

**signetics**

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Only the following product lines will be made available for military applications (i.e., applications requiring full military temperature range and/or specifications other than those on the device data sheets).

- 54 series
- 54S series
- 82 series (except as noted on the data sheet)
- 82S series (except as noted on the data sheet)
- 8T series (except as noted on the data sheet)
- Bipolar Memories: 82S06, 82S07

Linear devices will generally be available in military temperature range but such availability will be limited to ceramic DIP and T-05/T-03 can package configurations. Linear devices will not be available to environmental specifications other than Signetics standard production screening tests.

Your local Signetics representative will be happy to provide information on alternate devices and/or sources for discontinued military product types.



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82S30	8-Input Digital Multiplexer	MSI/TTL 8000	3-213
82S31	8-Input Digital Multiplexer	MSI/TTL 8000	3-213
82S32	8-Input Digital Multiplexer	MSI/TTL 8000	3-213
82S33	2-Input, 4-Bit Digital Multiplexer	MSI/TTL 8000	3-216
82S34	2-Input, 4-Bit Digital Multiplexer	MSI/TTL 8000	3-216
82S66	2-Input, 4-Bit Digital Multiplexer	MSI/TTL 8000	3-226
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2519	Hex 32-Bit and 40-Bit Static Shift Registers	MOS	7-75
2521	Dual 128-Bit/Dual 132-Bit Static Shift Registers	MOS	7-80
2522	Dual 128-Bit/Dual 132-Bit Static Shift Registers	MOS	7-80
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JAN 38510 Part Numbers—What They Mean

MILITARY DESIGNATOR	DETAIL SPECIFICATION	DEVICE TYPE	DEVICE CLASS	CASE OUTLINE	LEAD MATERIAL AND FINISH
JM38510	XXX	XX	X	X	X
Calls out Mil-M-38510A JAN I.C.	Refers to Detail Spec. 001,002, 003 ---  A slash sheet usually will contain more than 1 device type. Detail specs represent a grouping of devices by similar function.	Refers to one of the devices on the Detail Spec. 01, 02, 03---  This plus the detail spec will call out a specific part type such as a 5430, 5420 etc.	Device Class refers to level A,B, or C of MIL-Std-883.  The "X" will be a A,B or C, respectively	A = 1/4" X 1/4" Flat pack B = 1/4" X 1/8" Flat pack C = Dual-in-line, 14 pin D = 1/4" X 3/8" Flat pack E = Dual-in-line, 16 pin F = 16 pin flat pack G = 8 lead metal can H = 1/4" X 1/4" 10 lead Flat pack J = 10 lead metal can 3/8" X 1/2" 24 pin Flat pack J = Dual-in-line, 24 pin Z = 1/4" X 3/8" 24 pin Flat pack	A = Kovar or alloy 42 with Hot Solder Dip B = Kovar or alloy 42 with tin plate C = Kovar or alloy 42 with gold plate

Cross reference from case outline/lead material and finish (last two letters of 38510 part number) to Signetics' package type.

38510 Cross Reference To Basic Product (consult your Signetics' Sales Representative for a current QPL status)

SLASH SHEET	PRODUCT	SLASH SHEET	PRODUCT	SLASH SHEET	PRODUCT
38510/		38510/		38510/	
00101	5430	03	54164	02	54L20
02	5420	04	54165	03	54L10
03	5410	05	54194	04	54L00
04	5400	06	54195	05	54L04
05	5404				
06	5412	01001	5442	02101	54L71
07	5401	02	5443	02	54L72
08	5405	03	5444	03	54L73
09	5403	04	5445	04	54L78
		05	54145	05	54L74
00201	5472	06	5446		
02	5473	07	5447	02201	54H72
03	54107	08	5448	02	54H73
04	5476	09	5449	03	54H74
05	5474			04	54H76
06	5470	01101	54181	05	54H101
07	5479			06	54H103
		01201	54121		
00301	5440	02	54122	02301	54H30
02	5437	03	54123	02	54H20
03	5438			03	54H10

**MILITARY PRODUCTS**

**38510 Cross Reference To Basic Product (Continued)**

SLASH SHEET	PRODUCT	SLASH SHEET	PRODUCT	SLASH SHEET	PRODUCT
38510/		38510/		38510/	
03001	9930	05301	4007A	10201	723
02	9935	02	4019A		
03	9936			10301	710
03004	9946	05401	4008A	02	711
05	9962			03	106
				04	111
04001	54H50	05501	4009A		
02	54H51	02	4010A	10401	55107
03	54H53			02	55108
04	54H54	05601	4017A	03	9614
05	54H55	02	4018A	04	9615
04101	54L51	03	4020A		
02	54L54	04	4022A	10501	733
03	54L55	05	4024A		
				10601	LM102
05001	4011A	05701	4006A	02	LM110
02	4012A	02	4014A		
03	4023A	03	4015A	10701	LM109
		04	4021A		
05101	4013A	05	4031A		
02	4027A			20101	Hyprom 512
					MCM 5303
05201	4000A	10101	741	02	MCM 5304
02	4001A	02	747		
03	4002A	03	101A		
04	4025A	04	108A	20201	1024 Bit Prom
00401	5402	01301	5492	04	54H00
02	5423	02	5493	05	54H04
03	5425	03	54160	06	54H01
04	5427	04	54163	07	54H22
		05	54162		
00501	5450	06	54161	02401	54H40
02	5451	07	5490		
03	5453	08	54192	02501	54L90
04	5454	09	54193	02	54L93
00601	5482	01401	54150	02601	54L86
02	5483	02	9312/8230		
		03	54153	02701	54L02
00701	5486	04	9309		
		05	9322/54157	02801	54L95
00801	5406			02	54L164
02	5416	01501	5475		
03	5407	02	5477	02901	54L42
04	5417			02	54L43
		01601	5408	03	54L44
00901	5495	02	5409	04	54L46
02	5496			05	54L47
		02001	54L30		

## RB DISTRIBUTOR INVENTORY LIST

Signetics maintains in distributor inventory the following "RB" parts for immediate shipment. Overall level runs 200,000 pieces. Individual quantities are based upon historical sales mix and projected trends.

RB 5400F	RB 5480F	RB 54195F	RB 8234F
RB 5401F	RB 5483F	RB 54198F	RB 8235F
RB 5402F	RB 5486F	RB 54199F	RB 8241F
RB 5403F	RB 5490F		RB 8242F
RB 5404F	RB 5491F	RB 54H00F	RB 8250F
RB 5405F	RB 5492F	RB 54H01F	RB 8251F
RB 5406F	RB 5493F	RB 54H04F	RB 8252F
RB 5407F	RB 5494F	RB 54H05F	RB 8260F
RB 5408F	RB 5495F	RB 54H08F	RB 8261F
RB 5409F	RB 5496F	RB 54H10F	RB 8262F
RB 5410F	RB 54100I	RB 54H11F	RB 8263I
RB 5411F	RB 54107F	RB 54H20F	RB 8264I
RB 5413F	RB 54121F	RB 54H21F	RB 8266F
RB 5416F	RB 54123F	RB 54H22F	RB 8267F
RB 5417F	RB 54141F	RB 54H30F	RB 8268F
RB 5420F	RB 54145F	RB 54H40F	RB 8269F
RB 5421F	RB 54150I	RB 54H50F	RB 8270F
RB 5426F	RB 54153F	RB 54H51F	RB 8271F
RB 5430F	RB 54154F	RB 54H52F	RB 8273F
RB 5437F	RB 54155F	RB 54H53F	RB 8274F
RB 5438F	RB 54156F	RB 54H54F	RB 8275F
RB 5439F	RB 54157F	RB 54H55F	RB 8276F
RB 5440F	RB 54158F	RB 54H60F	RB 8280F
RB 5442F	RB 54160F	RB 54H61F	RB 8281F
RB 5443F	RB 54161F	RB 54H62F	RB 8284F
RB 5444F	RB 54162F	RB 54H71F	RB 8285F
RB 5445F	RB 54163F	RB 54H72F	RB 8288F
RB 5446F	RB 54164F	RB 54H73F	RB 8290F
RB 5447F	RB 54165F	RB 54H74F	RB 8291F
RB 5450F	RB 54166F	RB 54H76F	RB 8292F
RB 5451F	RB 54170F	RB 54H101F	RB 8293F
RB 5453F	RB 54174F	RB 54H102F	RB 8T09F
RB 5454F	RB 54175F	RB 54H103F	RB 8T10F
RB 5460F	RB 54180F	RB 54H106F	RB 8T13F
RB 5470F	RB 54181F	RB 54H108F	RB 8T14F
RB 5472F	RB 54182F		RB 8T15F
RB 5473F	RB 54192F	RB 8230F	RB 8T16F
RB 5474F	RB 54193F	RB 8331F	RB 8T18F
RB 5475F	RB 54194F	RB 8233F	RB 8T80F
RB 5476F			RB 8T90F





**signetics**

54/74  
PRODUCT  
SPECIFICATIONS

**2**





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## SCHOTTKY

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## 54/7400 PRODUCT INFORMATION

## GENERAL DESCRIPTION

**ABSOLUTE MAXIMUM RATINGS** (over operating free-air temperature range unless otherwise noted)

Supply Voltage $V_{CC}$ (See Note 1)	7V
Input Voltage, $V_{in}$ (See Note 1)	5.5V
Intermitter Voltage (See Note 2)	5.5V
Resistor Node Voltage, 54121, 74121 (See Note 1)	-5.5V to 7V
Operating Free-Air Temperature Range:	
Series 54 Circuits	-55°C to 125°C
Series 74 Circuits	0°C to 70°C
Storage Temperature Range	-65°C to 150°C

## NOTES:

1. Voltage values, except intermitter voltage, are with respect to network ground terminal.
2. This is the voltage between two emitters of a multiple-emitter transistor.
3. Output sink current tests 1 output at a time.

## Series 54/74 Logic Family

The 54/74XX logic family is medium speed TTL, and high speed TTL integrated circuits. The family includes a multiple number of functions in a variety of packages. The 54XX devices are characterized for the full military temperature range of -55°C to +125°C. The 74XX devices are characterized for the limited temperature range of 0°C to +70°C.

## INPUT CLAMPING DIODES

Although not shown on all schematic diagrams, all of these SSI circuits incorporate input diodes. Each clamping diode is capable of limiting negative excursions at the input to a maximum of 1.5 volts below ground, even if -12mA of current is drawn.

## DESIGN CONSIDERATIONS

## Logic Definition

Series 54/74 logic is defined in terms of standard POSITIVE LOGIC using the following definitions:

LOW VOLTAGE = LOGICAL "0"  
HIGH VOLTAGE = LOGICAL "1"

## Unused Inputs

For optimum switching times and minimum noise susceptibility unused inputs should be maintained at a positive voltage greater than 2.4V but not to exceed the absolute maximum rating of 5.5V. This eliminates the distributed capacitance associated with the floating-input-transistor emitter, bond wire, and package load, and ensures that no degradation will occur in the propagation delay times. Some possible ways of handling input emitters are:

1. Connect unused inputs to a supply voltage. Preferably, this voltage should be between 2.4V and 5.5V.
2. Connect unused inputs to a used input if maximum fanout of the driving output will not be exceeded. Each input presents a full load in the logical "1" state to the driving output.

## Input-Current Requirements

Input-current requirements reflect worst-case  $V_{CC}$  and temperature condition. Currents into the input terminals are specified as positive values.

## 54/74 Logic

Each input of the multiple-emitter input transistor that utilizes a 4 K $\Omega$  resistor requires no more than -1.6 mA flow out of the input at a logical "0" voltage level; therefore, one load (N = 1) for 54/74 logic is -1.6 mA maximum. Each input requires current into the input at a logical "1" voltage level. This current is 40 $\mu$ A maximum for each emitter input.

## Fanout Capability

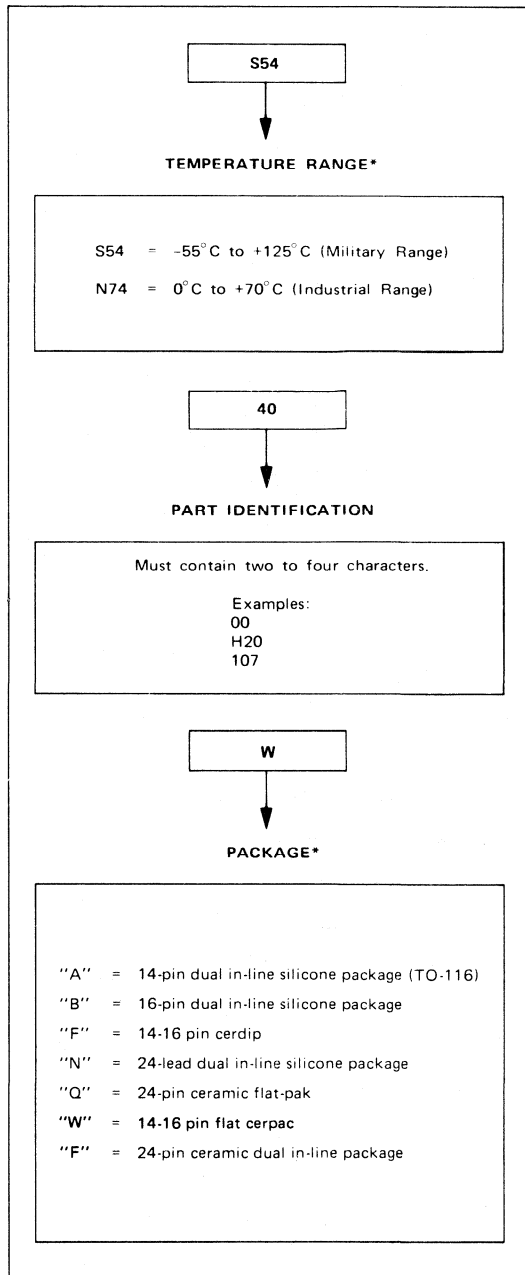
Fanout reflects the ability of an output to sink current from a number of loads (N) at a logical "0" voltage level and to supply current at a logical "1" voltage level. Each standard 54/74 output is capable of sinking current or supplying current to 10 loads (N = 10). The buffer gate (54/7440) is capable of sinking current or supplying current to 30 loads (N = 30).

## ELECTRICAL CHARACTERISTICS

These are guaranteed over the applicable operating free-air temperature range, unless otherwise noted, as shown in Section 2 of the handbook.

## NOTE

Any product available in an A or B package can also be supplied in the F cerdip package.



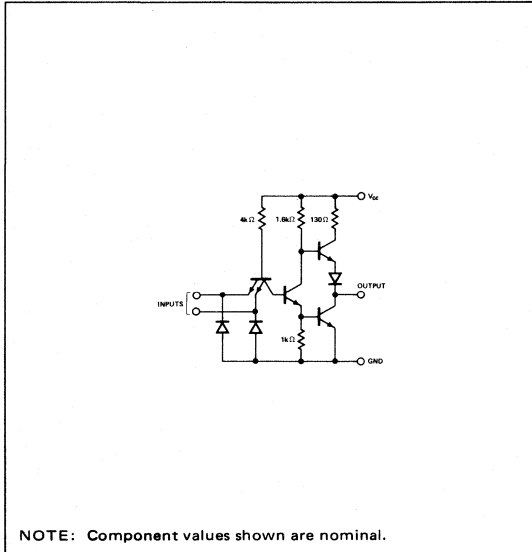
\*Availability of a circuit device in a particular package and temperature range is indicated on the appropriate device. Electrical Characteristics Data Sheet is shown in Section 2 of this handbook.

Manufacturer reserves the right to make design and process changes and improvements.

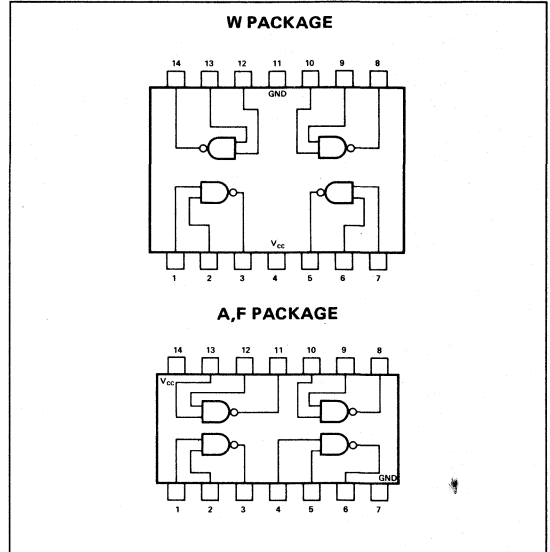
S5400-A,F,W • N7400-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :	S5400 Circuits	4.5	5	5.5	V
	N7400 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N	S5400 Circuits	-55	25	125	°C
	N7400 Circuits	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at both input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$		2			V
$V_{in(0)}$	Logical 0 input voltage required at either input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	$V_{in} = 0.8\text{V}$ ,	2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$	$V_{in} = 2\text{V}$ ,		0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$		S5400 N7400	-20 -18	-55 -55	mA

**SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND GATE ■ S5400, N7400**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

PARAMETER		TEST CONDITIONS *		MIN	TYP**	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		12	22	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		4	8	mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5V, T_A = 25^\circ C, N = 10$**

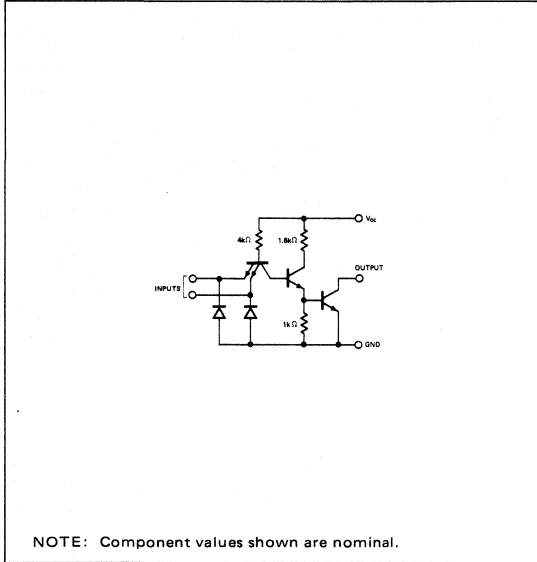
PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd(0)}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		7	15	ns
$t_{pd(1)}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		11	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.  
 \*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$   
 † Not more than one output should be shorted at a time.

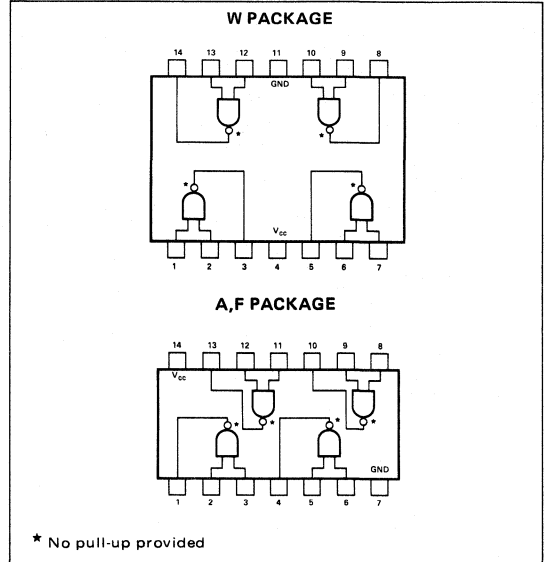
S5401-A,F,W • N7401-A,F

DIGITAL 54/74 TTL SERIES

**SCHEMATIC (each gate)**



**PIN CONFIGURATIONS**



**RECOMMENDED OPERATING CONDITIONS**

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5401 Circuits	4.5	5	5.5	V
N7401 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5401 Circuits	-55	25	125	°C
N7401 Circuits	0	25	70	°C

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at both input terminals to ensure logical 0 (on) level at output	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Logical 0 input voltage required at either input terminal to ensure logical 1 (off) level at output	$V_{CC} = \text{MIN}$		0.8	V
$I_{out(1)}$	Output reverse current	$V_{CC} = \text{MIN}$ , $V_{out(1)} = 5.5V$		250	$\mu A$
$V_{out(0)}$	Logical 0 output voltage (on level)	$V_{CC} = \text{MIN}$ , $I_{sink} = 16mA$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4V$		-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4V$ , $V_{in} = 5.5V$		40 1	$\mu A$ mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 5V$	12	22	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	4	8	mA



**SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND GATE ■ S5401, N7401**

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF$ ,	$R_L = 4 k\Omega$		35	45	ns

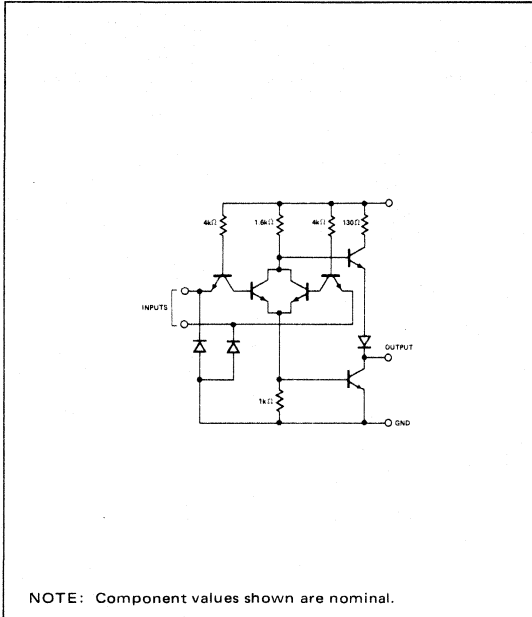
\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

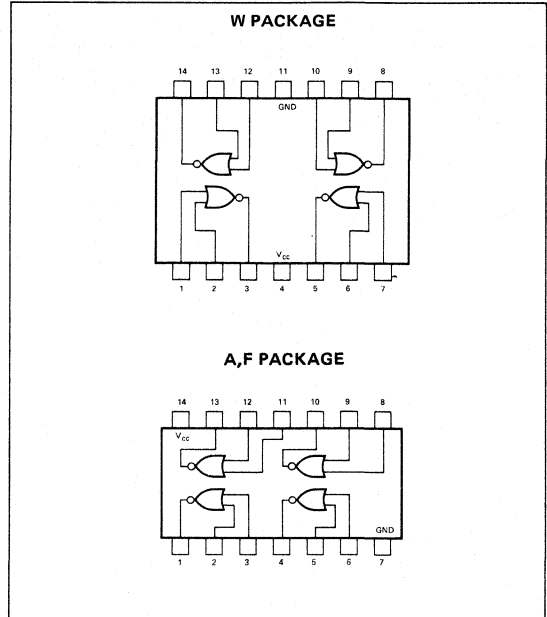


3

**SCHEMATIC (each gate)**



**PIN CONFIGURATIONS**



**RECOMMENDED OPERATING CONDITIONS**

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5402 Circuits	4.5	5	5.5	V
N7402 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5402 Circuits	-55	25	125	°C
N7402 Circuits	0	25	70	°C

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at either input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN}$			V
$V_{in(0)}$	Logical 0 input voltage required at both input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	$V_{in} = 0.8\text{V}$	2.4 3.3	V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$	$V_{in} = 2\text{V}$ ,	0.22 0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$		-1.6 mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$		40 $\mu\text{A}$ 1 mA
$I_{OS}$	Short circuit output Current†	$V_{CC} = \text{MAX}$	S5402 N7402	-20 -18	-55 -55 mA

**SIGNETICS QUADRUPLE 2-INPUT POSITIVE NOR GATE ■ S5402, N7402**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

PARAMETER		TEST CONDITIONS *		MIN	TYP	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		14	27	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		8	16	mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5V, T_A = 25^\circ C, N = 10$**

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		12	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$

† Not more than one output should be shorted at a time.

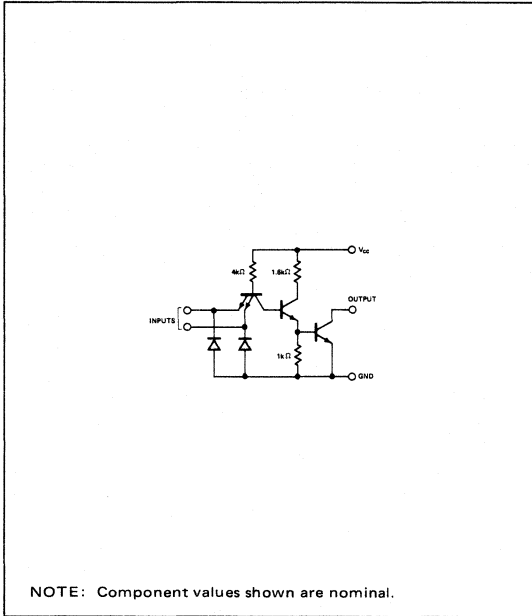
# signotics QUADRUPLE 2-INPUT POSITIVE NAND GATE WITH OPEN COLLECTOR OUTPUT

# S5403 N7403

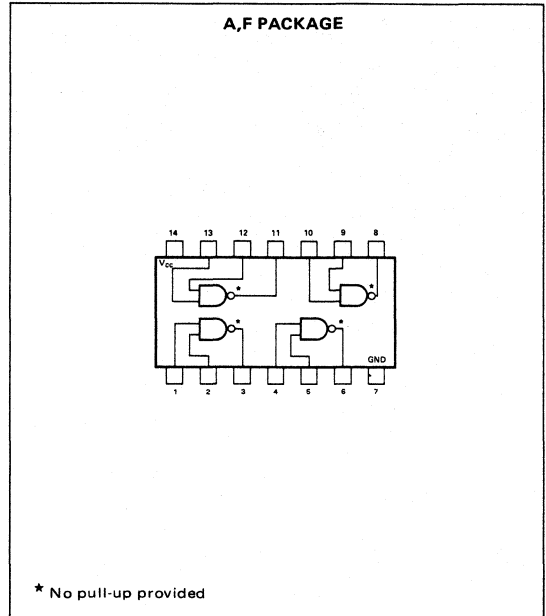
S5403-A,F • N7403-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

Supply Voltage $V_{CC}$ : S5403 Circuits N7403 Circuits	MIN	NOM	MAX	UNIT
	4.5	5	5.5	V
	4.75	5	5.25	V
			10	
Normalized Fan-Out from Output, N				
Operating Free-Air Temperature Range, $T_A$ : S5403 Circuits N7403 Circuits	-55	25	125	°C
	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at both input terminals to ensure logical 0 (on) level at output	$V_{CC} = \text{MIN}$		2	V
$V_{in(0)}$	Logical 0 input voltage required at either input terminal to ensure logical 1 (off) level at output	$V_{CC} = \text{MIN}$ , $V_{in} = 0.8V$		0.8	V
$I_{out(1)}$	Output reverse current	$V_{CC} = \text{MIN}$ , $V_{out(1)} = 5.5V$	$V_{in} = 2V$ ,	250	$\mu A$
$V_{out(0)}$	Logical 0 output voltage (on level)	$V_{CC} = \text{MIN}$ , $I_{sink} = 16mA$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4V$	-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4V$ , $V_{in} = 5.5V$	40 1	$\mu A$ mA

## SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND GATE ■ S5403, N7403

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS*		MIN	TYP	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5V$		12	22	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$		4	8	mA

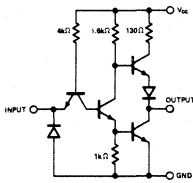
### SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^\circ C$ ,

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF$ ,	$R_L = 4 k\Omega$		35	45	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

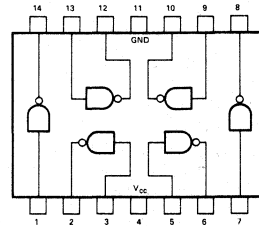
#### SCHEMATIC (each inverter)



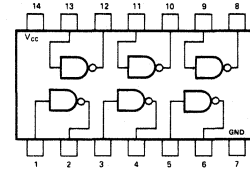
NOTE: Component values shown are nominal.

#### PIN CONFIGURATIONS

##### W PACKAGE



##### A,F PACKAGE



#### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5404 Circuits	4.5	5	5.5	V
N7404 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5404 Circuits	-55	25	125	°C
N7404 Circuits	0	25	70	°C

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	$V_{in} = 0.8\text{V}$ , 2.4	3.3	V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$	$V_{in} = 2\text{V}$ , 0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-1.6	mA
$I_{in(1)}$	Logical 1 level input current	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$		40 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$	S5404 N7404	-20 -18	-55 -65 mA

## ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS*		MIN	TYP	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5V$		18	33	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$		6	12	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ\text{C}$ ,  $N = 10$ 

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		12	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

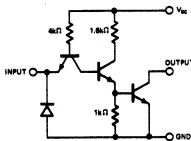
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

S5405-A,F,W • N7405-A,F

DIGITAL 54/74 TTL SERIES

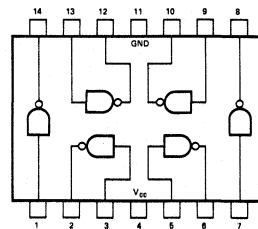
### SCHEMATIC (each inverter)



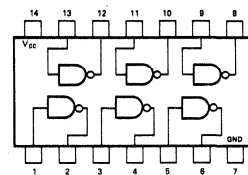
NOTE: Component values shown are nominal.

### PIN CONFIGURATIONS

#### W PACKAGE



#### A,F PACKAGE



### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5405 Circuits	4.5	5	5.5	V
N7405 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5405 Circuits	-55	25	125	°C
N7405 Circuits	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at input terminal to ensure logical 0 (on) level at output $V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Logical 0 input voltage required at input terminal to ensure logical 1 (off) level at output $V_{CC} = \text{MIN}$			0.8	V
$I_{out(1)}$	Output reverse current $V_{CC} = \text{MIN}$ , $V_{out(1)} = 5.5\text{V}$ $V_{in} = 0.8\text{V}$ ,			250	$\mu\text{A}$
$V_{out(0)}$	Logical 0 output voltage (on level) $V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$ $V_{in} = 2\text{V}$ ,			0.4	V
$I_{in(0)}$	Logical 0 level input current $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current $V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{CC(0)}$	Logical 0 level supply current $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ $V_{in} = 5\text{V}$ ,		18	33	mA
$I_{CC(1)}$	Logical 1 level supply current $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ $V_{in} = 0$ ,		6	12	mA



## SIGNETICS HEX INVERTER WITH OPEN COLLECTOR OUTPUT ■ S5405, N7405

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF$ ,	$R_L = 4 k\Omega$		40	55	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

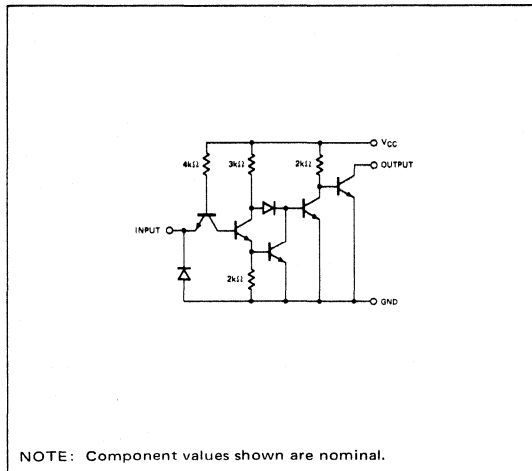
S5406-A,F,W • S5416-A,F,W • N7406-A,F • N7416-A,F

DIGITAL 54/74 TTL SERIES

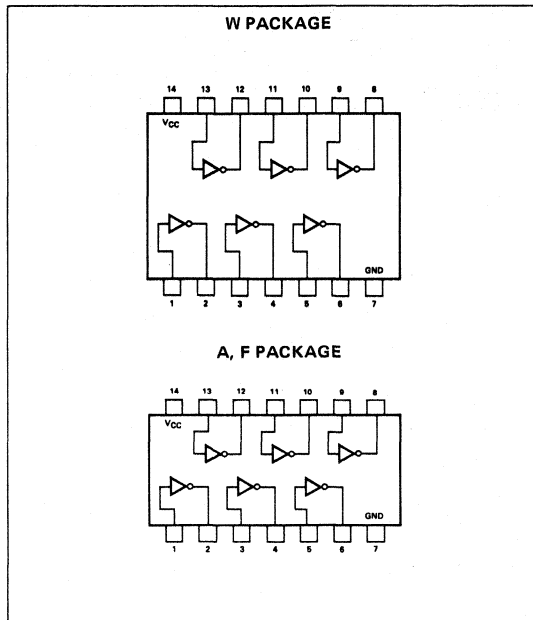
#### DESCRIPTION

The 54/7406 and 54/7416 Hex Inverter Buffer/Drivers features standard TTL inputs with inverted high voltage, high current, open collector outputs for interface with MOS, lamps or relays. The 54/7406 minimum output breakdown is 30 volts and the 54/7416 minimum output breakdown is 15 volts.

#### SCHEMATIC (each inverter)



#### PIN CONFIGURATIONS



#### RECOMMENDED OPERATING CONDITIONS

	S5406, S5416			N7406, N7416			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Output Voltage, $V_{OH}$ : S5406, N7406			30			30	
S5416, N7416			15			15	V
Low-level output current, $I_{OL}$			30			40	mA
Operating Free-air Temperature Range, $T_A$	-55	25	125	0	25	70	$^{\circ}C$

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage		2		V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{OH}$	High-level output current	$V_{CC} = \text{MIN}, V_I = 0.8V, V_{OH} = \text{MAX}$		250	$\mu A$
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_I = 2V, I_{OL} = \text{MAX}$		0.7	V
		$V_{CC} = \text{MIN}, V_I = 2V, I_{OL} = 16mA$		0.4	V
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4V$		40	$\mu A$
(each input)		$V_{CC} = \text{MAX}, V_I = 5.5V$		1	mA
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4V$		-1.6	mA
(each input)					
$I_{CCH}$	Supply current, high-level output	$V_{CC} = \text{MAX}, V_I = 0$	30	42	mA
$I_{CCL}$	Supply current, low-level output	$V_{CC} = \text{MAX}, V_I = 5V$	27	38	mA

**SIGNETICS HEX INVERTER BUFFER/DRIVER ■ S5406, S5416, N7406, N7416**

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$ , $R_L = 110 \Omega$		10	15	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15pF$ , $R_L = 110 \Omega$		14	23	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .



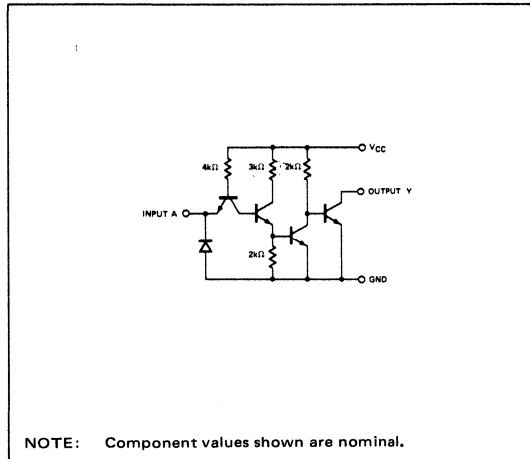
S5407-A,F,W • S5417-A,F,W • N7407-A,F • N7417-A,F

DIGITAL 54/74 TTL SERIES

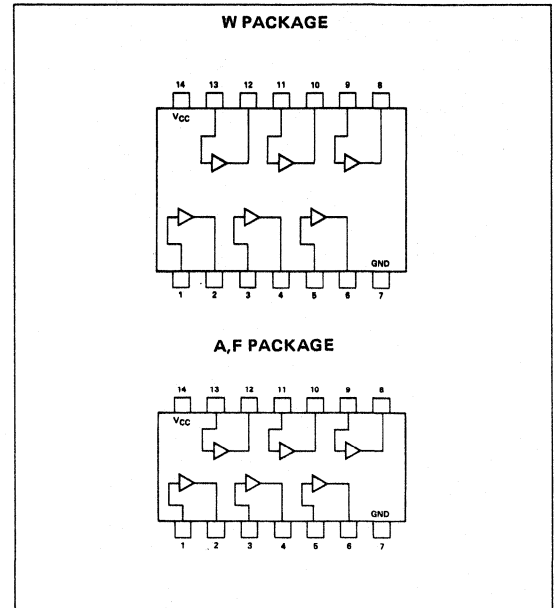
#### DESCRIPTION

The 54/7407 and 54/7417 Hex Buffer/Driver features standard TTL inputs with non-inverted high voltage, high current open collector outputs for interface with MOS, lamps or relays. The 54/7407 minimum output is 30 volts and the 54/7417 minimum output is 15 volts.

#### SCHEMATIC (each buffer/driver)



#### PIN CONFIGURATIONS



#### RECOMMENDED OPERATING CONDITIONS

	S5407, S5417			N7407, N7417			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Output Voltage, $V_{OH}$ : S5407, N7407			30			30	V
S5417, N7417			15			15	V
Low-Level Output Current, $I_{OL}$			30			40	mA
Operating Free-Air Temperature Range, $T_A$	-55	25	125	0	25	70	°C

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$I_{OH}$ High-level output current	$V_{CC} = \text{MIN}, V_1 = 2V, V_{OH} = \text{MAX}$			250	$\mu A$
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_1 = 0.8V, I_{OL} = \text{MAX}$			0.7	V
	$V_{CC} = \text{MIN}, V_1 = 0.8V, I_{OL} = 16\text{mA}$			0.4	V
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_1 = 2.4V$			40	$\mu A$
(each input)	$V_{CC} = \text{MAX}, V_1 = 5.5V$			1	mA
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_1 = 0.4V$			-1.6	mA
(each input)					
$I_{CCH}$ Supply current, high-level output	$V_{CC} = \text{MAX}, V_1 = 5V$		29	41	mA
$I_{CCL}$ Supply current, low-level output	$V_{CC} = \text{MAX}, V_1 = 0$		21	30	mA

**SIGNETICS HEX BUFFER/DRIVER ■ S5407, S5417, N7407, N7417**

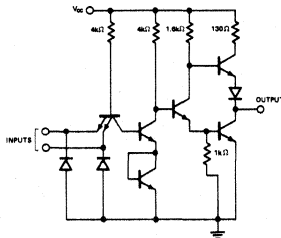
SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$ ,	$R_L = 110\Omega$		6	10	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15pF$ ,	$R_L = 110\Omega$		20	30	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

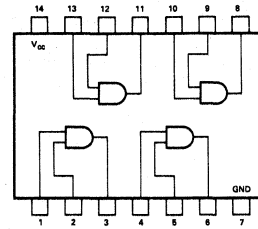
SCHEMATIC (each gate)



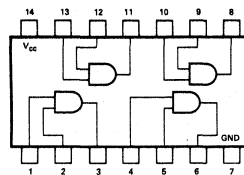
NOTE: Component values shown are nominal.

PIN CONFIGURATIONS

W PACKAGE



A PACKAGE



RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5408 Circuits	4.5	5	5.5	V
N7408 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5408 Circuits	-55	25	125	$^{\circ}$ C
N7408 Circuits	0	25	70	$^{\circ}$ C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at both input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Logical 0 input voltage required at either input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -800\mu\text{A}$	$V_{in} = 2.0\text{V}$ , 2.4	3.3	V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$	$V_{in} = 0.8\text{V}$ , 0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$	$V_{in} = 0.4\text{V}$	-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$	$V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$	40 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$	S5408 N7408	-20 -18	mA

## SIGNETICS QUADRUPLE 2-INPUT POSITIVE AND GATES ■ S5408, N7408

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS *		MIN	TYP**	MAX	UNIT
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		10	15	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		18	26	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		12	19	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		17.5	27	ns

- \* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.
- \*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$
- † Not more than one output should be shorted at a time.

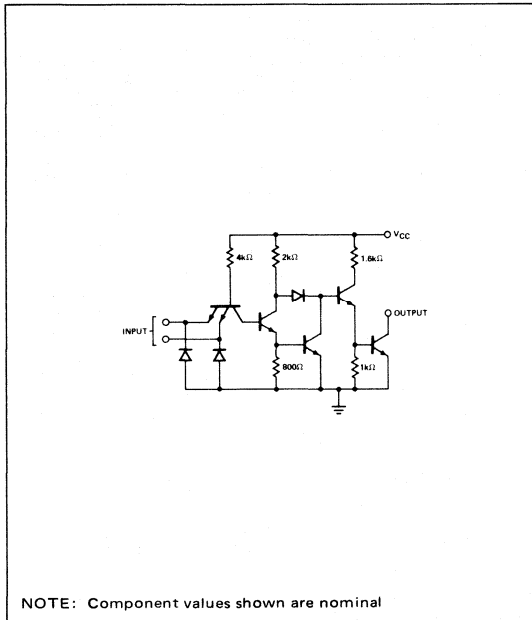
S5409-A,F,W • N7409-A,F

DIGITAL 54/74 TTL SERIES

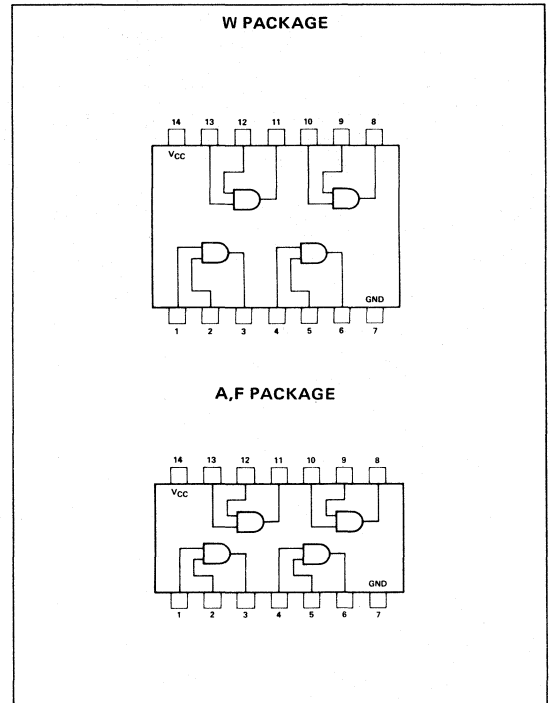
### DESCRIPTION

The 54/7409 Quad 2-Input AND Gate with open collector outputs provides the capability of expanding AND logic functions.

### SCHEMATIC (each gate)



### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

	S5409			N7409			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10			10	
Operating Free-Air Temperature Range, $T_A$	-55	25	125	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT	
$V_{IH}$	High-level input voltage	2			V	
$V_{IL}$	Low-level input voltage			0.8	V	
$I_{OH}$	High-level output current			250	mA	
$V_{OL}$	Low-level output voltage			0.4	V	
$I_{IH}$	High-level input current (each input)	$V_{CC} = \text{MIN}, V_{IH} = 2V, V_{OH} = 5.5V$		40	μA	
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MIN}, V_{IL} = 0.8V, I_{OL} = 16mA$		1	mA	
$I_{CCH}$	Supply current, high-level output	$V_{CC} = \text{MAX}, V_1 = 2.4V$				
$I_{CCL}$	Supply current, low-level output	$V_{CC} = \text{MAX}, V_1 = 5.5V$				
		$V_{CC} = \text{MAX}, V_1 = 0.4V$		10	15	mA
		$V_{CC} = \text{MAX}, V_1 = 5V$		18	26	mA



## SIGNETICS QUAD 2-INPUT AND GATE WITH OPEN COLLECTOR OUTPUTS ■ S5409, N7409

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$		21	32	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output	$R_L = 400 \Omega$		16	24	ns

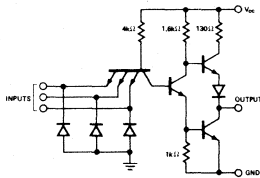
\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

S5410-A,F,W • N7410-A,F

DIGITAL 54/74 TTL SERIES

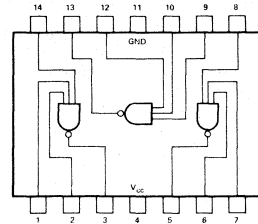
SCHEMATIC (each gate)



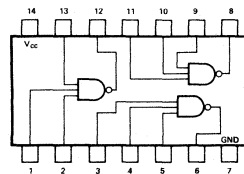
NOTE: Component values shown are nominal.

PIN CONFIGURATIONS

W PACKAGE



A,F PACKAGE



RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :	S5410 Circuits	4.5	5	5.5	V
	N7410 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N				10	
Operating Free-Air Temperature Range, $T_A$ :	S5410 Circuits	-55	25	125	$^{\circ}$ C
	N7410 Circuits	0	25	70	$^{\circ}$ C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$		2			V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	$V_{in} = 0.8\text{V}$ ,	2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$	$V_{in} = 2\text{V}$ ,		0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = 5.5\text{V}$		S5410 N7410	-20 -18	-55 -55	mA

## SIGNETICS TRIPLE 3-INPUT POSITIVE NAND GATE ■ S5410, N7410

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS *		MIN	TYP **	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX.}$	$V_{in} = 5V$		9	16.5	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX.}$	$V_{in} = 0$		3	6	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^\circ C$ , $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		7	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		11	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

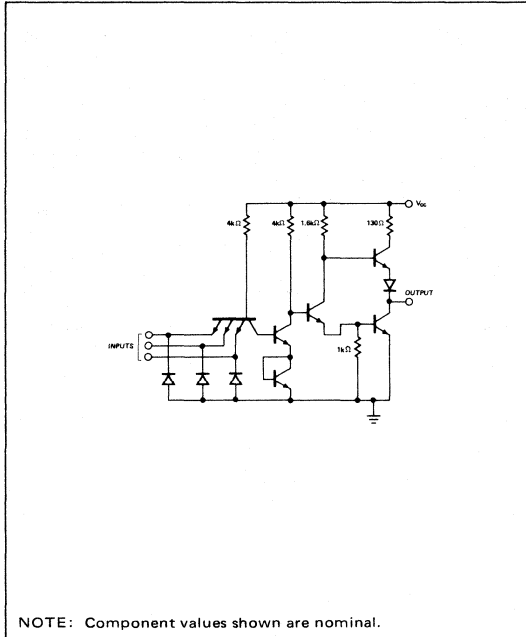
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

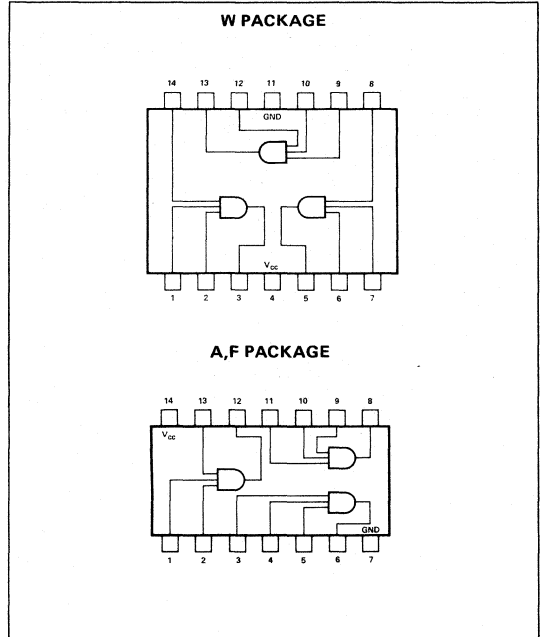
S5411-A,F,W • N7411-A,F

DIGITAL 54/74 TTL SERIES

### SCHEMATIC DIAGRAM



### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5411 Circuits	4.5	5	5.5	V
N7411 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5411 Circuits	-55	25	125	$^{\circ}$ C
N7411 Circuits	0	25	70	$^{\circ}$ C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN}$	2		V	
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN}$		0.8	V	
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ $I_{load} = -800\mu\text{A}$	$V_{in} = 2.0\text{V}$ , 2.4	3.3	V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ $I_{sink} = 16\text{mA}$	$V_{in} = 0.8\text{V}$ , 0.22	0.4	V	
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$	$V_{in} = 0.4\text{V}$	-1.6	mA	
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ $V_{CC} = \text{MAX}$	$V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$	40 1	$\mu\text{A}$ mA	
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$	S5411 N7411	-20 -18	-55 -55	mA

## SIGNETICS TRIPLE 3-INPUT POSITIVE AND GATE ■ S5411, N7411

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5V$		7.5	12	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$		13.5	20	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^\circ C$ , $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		12	19	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		17.5	27	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

† Not more than one output should be shorted at a time.

S5413-A,F,W • N7413-A,F

DIGITAL 54/74 TTL SERIES

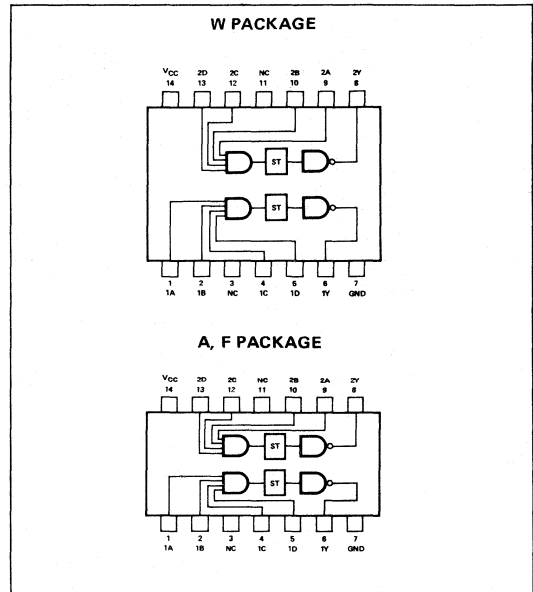
### DESCRIPTION

The 5413 and 7413 dual Schmitt triggers consist of two identical Schmitt-trigger circuits in monolithic integrated circuit form. Logically, each circuit functions as a four-input NAND gate, but because of the Schmitt action, the gate has different input threshold levels for positive- and negative-going signals. The hysteresis, or backlash, which is the difference between the two threshold levels, is typically 800mV.

An important design feature is the built-in temperature compensation which ensures very high stability of the threshold levels and the hysteresis over a very wide temperature range. Typically, the hysteresis changes by 3% over the temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$  and the upper threshold changes by 1% over the same range. The 5413/7413 can be triggered from the slowest of input ramps and still give clean, jitter-free output signals. It can not be triggered from straight dc levels.

These circuits are fully compatible with most other TTL, DTL, or MSI circuits. The 5413 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 7413 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### PIN CONFIGURATION



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	5413			7413			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Fan-Out From Each Output, N							
High Logic Level			20			20	
Low Logic Level			10			10	
Operating Free-Air Temperature Range, $T_A$	-55	0	125	0	25	70	$^{\circ}\text{C}$
Maximum Input Rise and Fall Times	No Restriction			No Restriction			

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{T+}$	Positive-going threshold voltage	$V_{CC} = 5\text{V}$	1.5	1.7	2	V
$V_{T-}$	Negative-going threshold voltage	$V_{CC} = 5\text{V}$	0.6	0.9	1.1	V
$V_{T+} - V_{T-}$	Hysteresis	$V_{CC} = 5\text{V}$	0.4	0.8		V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN},$ $I_I = -12\text{mA}$			-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN},$ $I_{OH} = -800\mu\text{A}$	2.4	3.3		V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN},$ $I_{OL} = 16\text{mA}$		0.22	0.4	V
$I_{T+}$	Input current at positive-going threshold	$V_{CC} = 5\text{V},$ $V_I = V_{T+}$		-0.65		mA
$I_{T-}$	Input current at negative-going threshold	$V_{CC} = 5\text{V},$ $V_I = V_{T-}$		-0.85		mA
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX},$ $V_I = 5.5\text{V}$			1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX},$ $V_I = 2.4\text{V}$			40	$\mu\text{A}$
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX},$ $V_I = 0.4\text{V}$			-1.6	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX},$	-18		-55	mA
$I_{CCH}$	Supply current, high-level output	$V_{CC} = \text{MAX},$ $V_I = 0$		14	23	mA
$I_{CCL}$	Supply current, low-level output	$V_{CC} = \text{MAX},$ $V_I = 4.5\text{V}$		20	32	mA

# SIGNETICS DUAL NAND SCHMITT TRIGGER ■ S5413, N7413

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

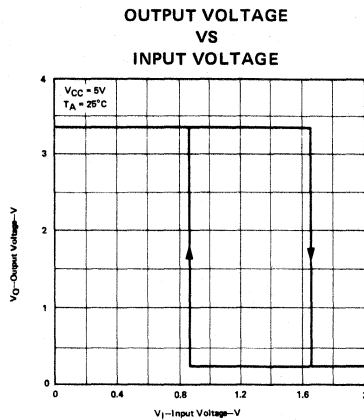
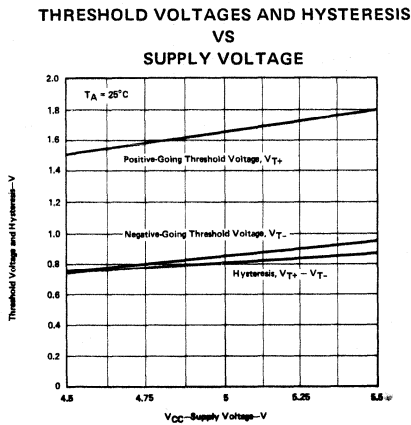
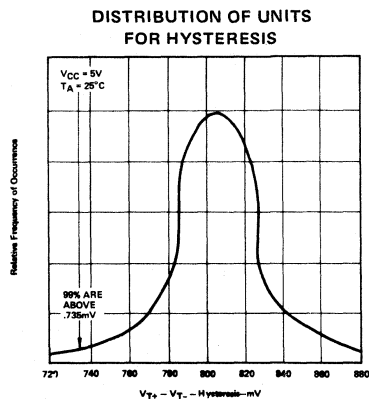
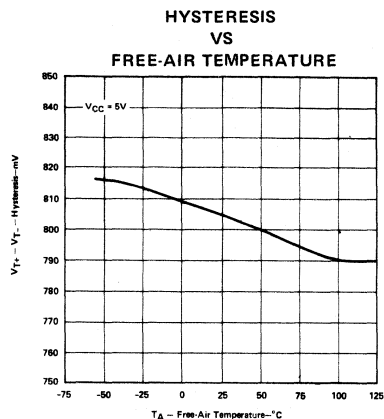
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output $C_L = 15pF$ , $R_L = 400\Omega$		18	27	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output $C_L = 15pF$ , $R_L = 400\Omega$		15	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

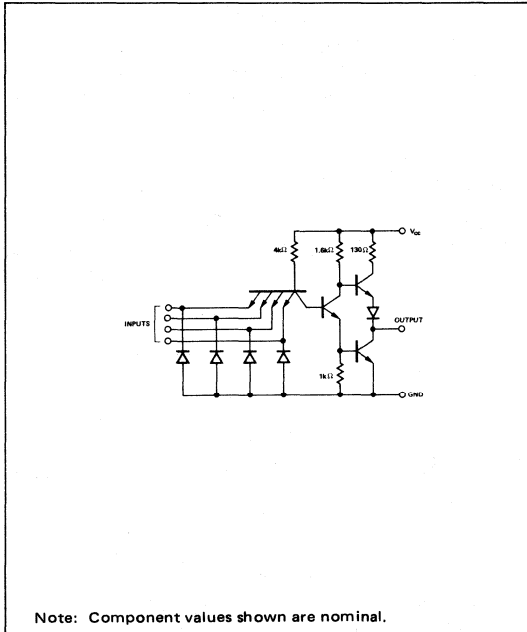
## TYPICAL CHARACTERISTICS



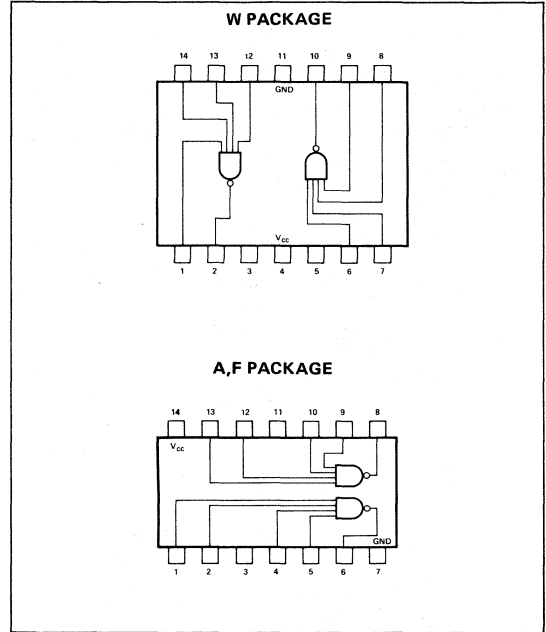
S5420-A,F,W • N7420-A,F

DIGITAL 54/74 TTL SERIES

**SCHEMATIC (each gate)**



**PIN CONFIGURATIONS**



**RECOMMENDED OPERATING CONDITIONS**

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5420 Circuits	4.5	5	5.5	V
N7420 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5420 Circuits	-55	25	125	°C
N7420 Circuits	0	25	70	°C

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output $V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 level at output $V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$ $V_{in} = 0.8\text{V}$ ,	2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$ $V_{in} = 2\text{V}$ ,		0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input) $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input) $V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current† $V_{CC} = \text{MAX}$ ,	S5420 N7420	-20 -18	-55 -55	mA



## SIGNETICS DUAL 4-INPUT POSITIVE NAND GATE ■ S5420, N7420

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		6	11	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		2	4	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		12	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

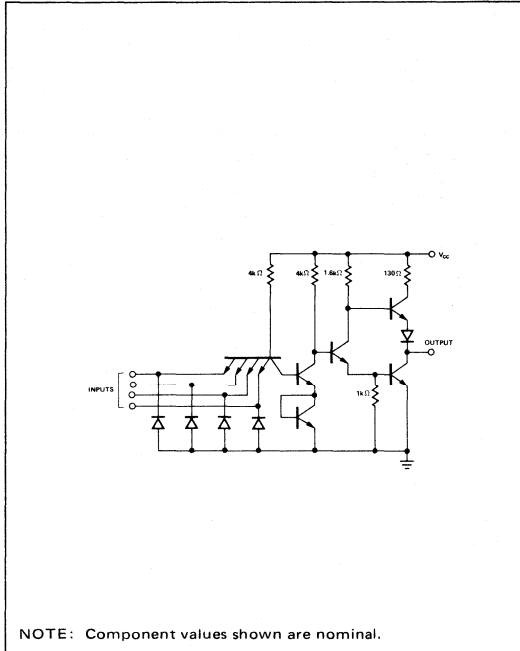
\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C.$

† Not more than one output should be shorted at a time.

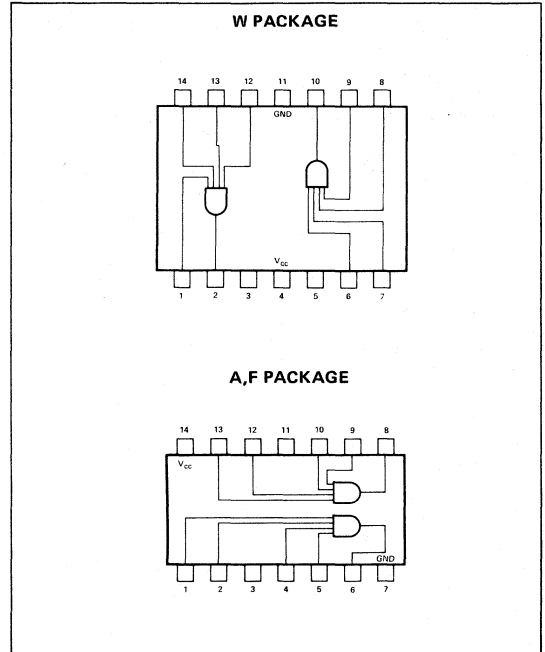
S5421-A,F,W • N7421-A,F

DIGITAL 54/74 TTL SERIES

### SCHEMATIC DIAGRAM



### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :	S5421 Circuits	4.5	5	5.5	V
	N7421 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N				10	
Operating Free-Air Temperature Range, $T_A$ :	S5421 Circuits	-55	25	125	°C
	N7421 Circuits	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN}$		2			V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN}$				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN},$ $I_{load} = -800\mu\text{A}$	$V_{in} = 2.0\text{V},$	2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage		$V_{in} = 0.8\text{V}$		0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$ $I_{sink} = 16\text{mA}$	$V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)		$V_{in} = 2.4\text{V}$			40	$\mu\text{A}$
$I_{OS}$	Short circuit output	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$	$V_{in} = 5.5\text{V}$		1		mA
			S5421	-20		-55	mA
		N7421		-18		-55	mA

**SIGNETICS DUAL 4-INPUT POSITIVE AND GATE ■ S5421, N7421**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

PARAMETER		TEST CONDITIONS *		MIN	TYP **	MAX	UNIT
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5V$		5	8	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$		9	13	mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$**

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		12	19	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF$ ,	$R_L = 400\Omega$		17.5	27	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

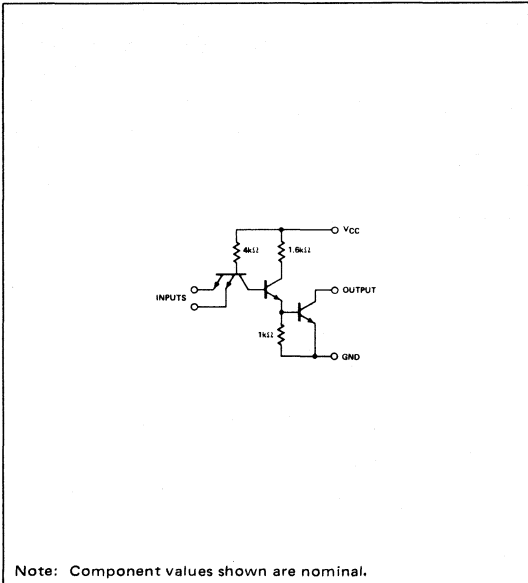
S5426-A,F • N7426-A,F

DIGITAL 54/74 TTL SERIES

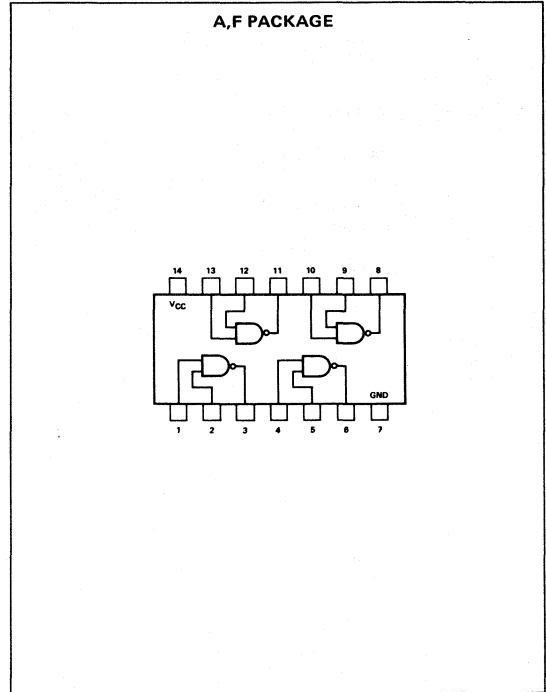
### DESCRIPTION

The 54/7426 Quad 2-Input NAND Gate features standard TTL inputs with high voltage (15 volts) open collector outputs for interface with MOS, lamps or relays.

### SCHEMATIC (each gate)



### PIN CONFIGURATION



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S5426			N7426			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage	4.5	5	5.5	4.75	5	5.25	V
Output Voltage, $V_{OH}$			15			15	V
Low-Level Output Current, $I_{OL}$			16			16	mA
Operating Free-Air Temperature Range, $T_A$	-55	25	125	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage		2		V
$V_{IL}$	Low-level input voltage			0.8	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 0.8V, I_{OH} = 1mA$	15		V
$I_{OH}$	High-level output current	$V_{CC} = \text{MIN}, V_{IL} = 0.8V, V_{OH} = 12V$		50	μA
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2V, I_{OL} = 16mA$		0.4	V
$I_{IH}$	High-level input current (each input)	$V_{CC} = \text{MAX}, V_1 = 2.4V$		40	μA
		$V_{CC} = \text{MAX}, V_1 = 5.5V$		1	mA
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MAX}, V_1 = 0.4V$		-1.6	mA
$I_{CCH}$	Supply current, high-level output	$V_{CC} = \text{MAX}, V_1 = 0$	4	8	mA
$I_{CCL}$	Supply current, low-level output	$V_{CC} = \text{MAX}, V_1 = 5V$	12	22	mA

**SIGNETICS QUAD 2-INPUT HIGH VOLTAGE NAND GATE ■ S5426, N7426**

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$ ,	$R_L = 1k\Omega$		16	24	ns
$t_{PHL}$	Propagation delay time high-to-low-level output	$C_L = 15pF$ ,	$R_L = 1k\Omega$		11	17	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

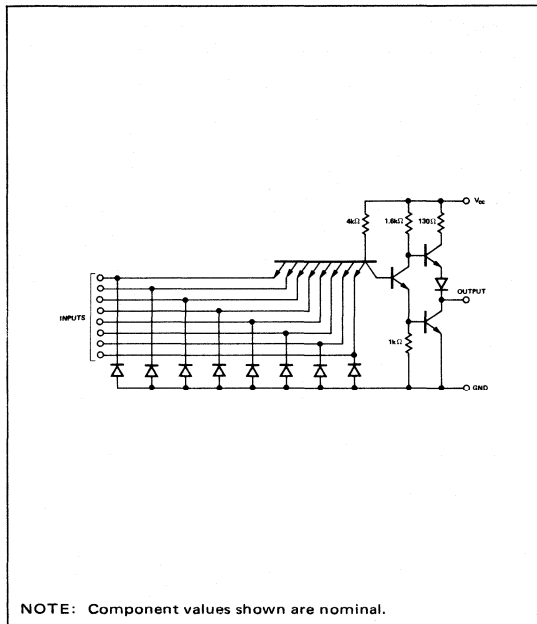
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .



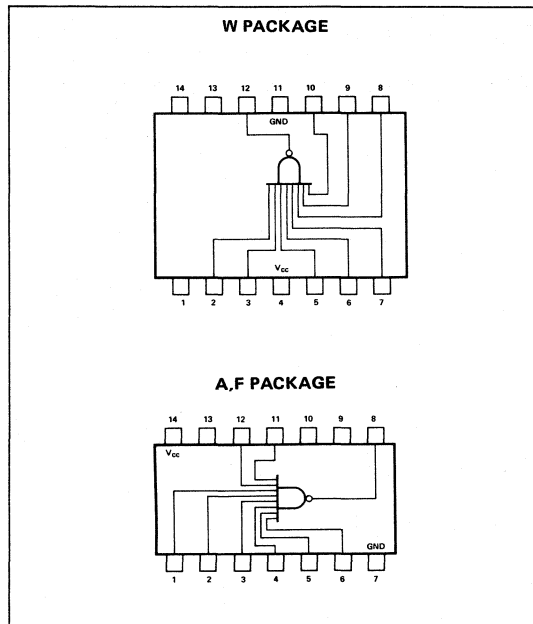
S5430-A,F,W • N7430A,F

DIGITAL 54/74 TTL SERIES

### SCHEMATIC DIAGRAM



### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5430 Circuits	4.5	5	5.5	V
N7430 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5430 Circuits	-55	25	125	°C
N7430 Circuits	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT		
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$		2	V		
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$		0.8	V		
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	$V_{in} = 0.8\text{V}$ ,	2.4	3.3	V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$	$V_{in} = 2\text{V}$ ,	0.22	0.4	V	
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$		-1.6	mA	
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$		40	$\mu\text{A}$	
		$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5\text{V}$		1	mA	
$I_{OS}$	Short circuit output current †	$V_{CC} = \text{MAX}$ ,		S5430	-20	-55	mA
				N7430	-18	-55	

## SIGNETICS 8-INPUT POSITIVE NAND GATE ■ S5430, N7430

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		3	6	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		1	2	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		13	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

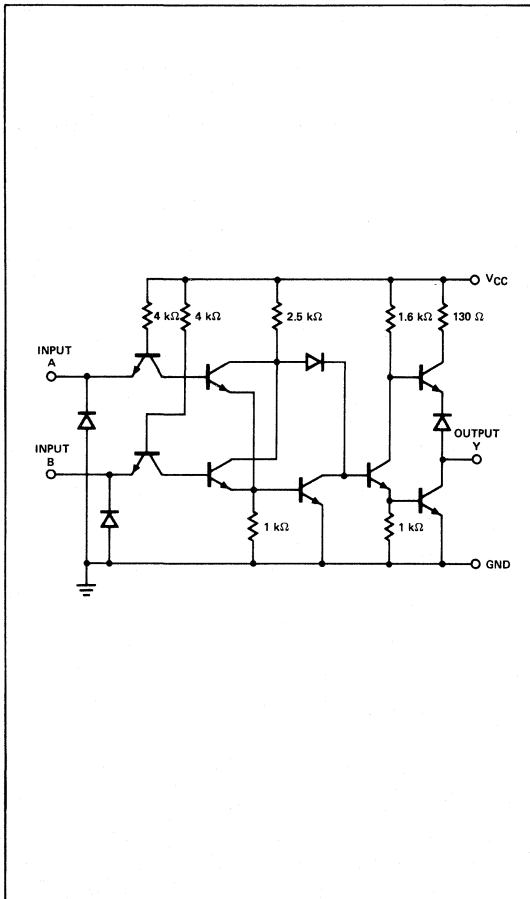
S5432F/W/A • N7432A/F

DIGITAL 54/74 TTL SERIES

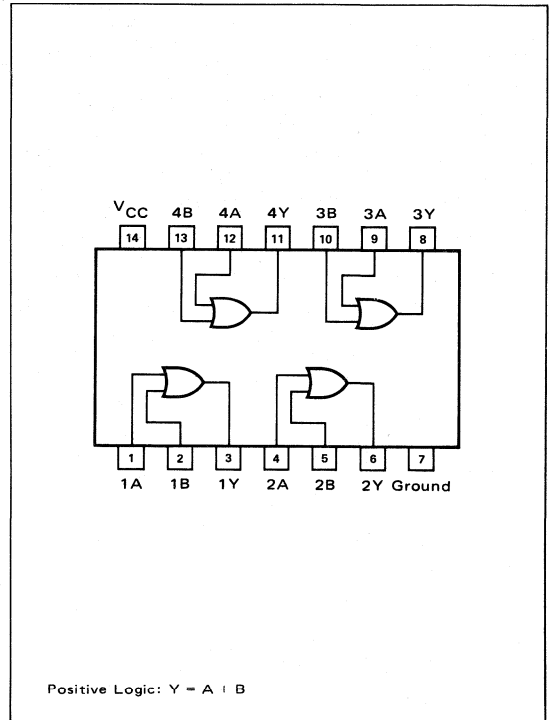
### DESCRIPTION

The 54/7432 provides four 2 input or logic functions. Each gate may be used individually or connected serially to provide an equivalent five input or function.

### SCHEMATIC (Each gate)



### PIN CONFIGURATION (Top View) \*



\*Pin assignments for these circuits are the same for all packages.

### ABSOLUTE MAXIMUM RATINGS

Supply voltage,  $V_{CC}$  (see Note 1) . . . . . 7 V  
 Input voltage . . . . . 5.5 V  
 Operating free-air temperature range:  
     5432 Circuits . . . . .  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$   
     7432 Circuits . . . . .  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$   
 Storage temperature range . . . . .  $-65^{\circ}\text{C}$  to  $150^{\circ}\text{C}$

#### NOTE:

1. Voltage values are with respect to network ground terminal.

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	5432			7432			UNIT
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20	Low logic level		10	
	Low logic level		10	High logic level		20	
Operating free-air temperature, $T_A$	-55	25	125	0	25	70	$^{\circ}\text{C}$



## ELECTRICAL CHARACTERISTICS

PARAMETER		TEST CONDITIONS†	MIN.	TYP‡	MAX.	UNIT
V <sub>IH</sub>	High-level input voltage		2			V
V <sub>IL</sub>	Low-level input voltage				0.8	V
V <sub>I</sub>	Input clamp voltage	V <sub>CC</sub> = MAX. I <sub>I</sub> = -12 mA			-1.5	V
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN. V <sub>IH</sub> = 2 V, I <sub>OH</sub> = -800 μA	2.4	3.3		V
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 16 mA		0.22	0.4	V
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V			1	mA
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX. V <sub>I</sub> = 2.4 V			40	μA
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V			-1.6	mA
I <sub>OS</sub>	Short-circuit output current §	V <sub>CC</sub> = MAX	5432	-20	-56	mA
			7432	-18	-55	
I <sub>CCH</sub>	Supply current, high-level output	V <sub>CC</sub> = MAX, See Note 2		15	22	mA
I <sub>CCL</sub>	Supply current, low-level output	V <sub>CC</sub> = MAX, See Note 3		23	38	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type

‡ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C.

§ Not more than one output should be shorted at a time.

NOTES: 2. I<sub>CCH</sub> is measured with one input of each gate at 4.5 V, the remaining inputs grounded, and outputs open.

3. I<sub>CCL</sub> is measured with both inputs of all gates grounded, and outputs open.

SWITCHING CHARACTERISTICS V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C, N = 10

PARAMETER		TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
t <sub>PHL</sub>	Propagation delay time, high-to-low-level output	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 400 Ω		14	22	ns
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output			10	15	ns

S5437-A,F,W • S5438-A,F,W • S5439-A,F • N7437-A,F,W • N7438-A,F • N7439-A,F

### DESCRIPTION

The S5437/N7437 is a NAND Gate (output low only when all inputs are high) the same as N7400 except that it will drive 3 times as many loads. The S5438/N7438 and S5439/N7439 are also NAND Gates but have open-collectors similar to N7403.

The S5437/N7437, S5438/N7438 and S5439/N7439 contain four 2-input NAND gates in a package with a guaranteed fan-out of 30-series 54/74 loads in both the logical "1" (1.2mA), and logical "0" (48mA) states. The S5438/N7438 and S5439/N7439 have an open collector output for "WIRE-AND" applications but still retain the high sink current capability of the S5437/N7437.

**ABSOLUTE MAXIMUM RATINGS** (over operating temperature ranges unless otherwise noted)

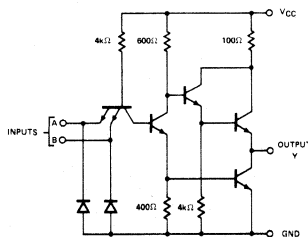
Supply Voltage $V_{CC}$ (See Note 1)	7V
Supply Voltage (See Note 1)	5.5V
Interrmitter Voltage (See Note 2)	5.5V
Output Voltage (See Notes 1 and 3): S5438/N7438, S5439/N7439	5.5V
Operating Free-Air Temperature Range: S5437/S5438/S5439	-55°C to 125°C
N7437/N7438/N7439	0°C to 70°C
Storage Temperature Range	-65°C to 150°C

### NOTES:

1. Voltage values, except intermitter voltage, are with respect to network ground terminal.
2. This is the voltage between two emitters of a multiple-emmitter transistor.
3. This is the maximum voltage which should be applied to any output when it is in the off state.

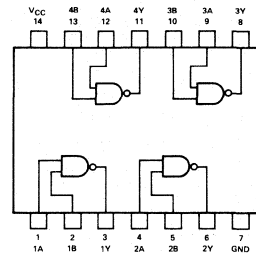
### SCHEMATICS (each buffer)

S5437, N7437 (Totem-Pole Output)

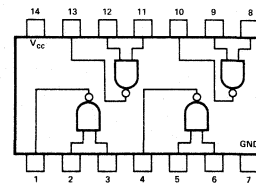


### PIN CONFIGURATIONS

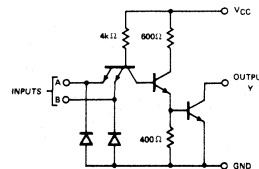
A, F, W PACKAGE  
54/7437/38



A, F PACKAGE  
54/7439



S5438, N5438, S5439, N7439 (Open-Collector Output)



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S5437, S5438, S5439			N7437, N7438, N7439			UNIT
	MIN	TYP	MAX	MIN	TYP	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			30			30	
Operating Free-Air Temperature Range, $T_A$	-55	25	125	0	25	70	°C

# SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND BUFFER ■ SN54/7437, SN54/7438, SN43/7439

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *		MIN	TYP **	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MIN},$	$I_I = -12\text{mA}$ $V_{IL} = 0.8\text{V}$			-1.5	V
$V_{OH}$	High-level output voltage		$I_{OH} = 1.2\text{mA}$	2.4	3.3		V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN},$ $I_{OL} = 48\text{mA}$	$V_{IH} = 2\text{V}$		0.22	0.4	V
$I_I$	Input current at max. input voltage	$V_{CC} = \text{MAX},$	$V_I = 5.5\text{V}$			1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX},$	$V_I = 2.4\text{V}$			40	$\mu\text{A}$
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX},$	$V_I = 0.4\text{V}$			-1.6	mA
$I_{OS}$	Short-circuit output current	$V_{CC} = \text{MAX}$		-20		-55	mA
				-18		-55	mA
$I_{CCH}$	Supply current, high-level output	$V_{CC} = \text{MAX},$	See Note 2		9	15.5	mA
$I_{CCL}$	Supply current, low-level output	$V_{CC} = \text{MAX},$	See Note 3		34	54	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER 54/7437		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 45\text{pF},$ $R_L = 133\Omega$			8	15	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output				13	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}.$

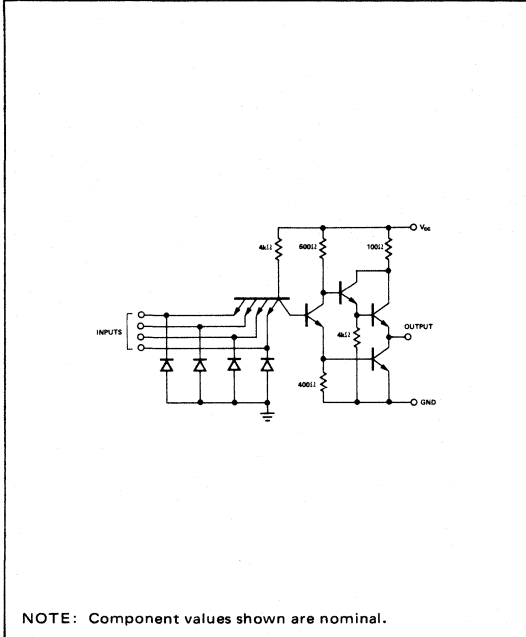
† Not more than one output should be shorted at a time.

PARAMETER 54/7438/39		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 45\text{pF},$ $R_L = 133\Omega$			14	22	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output				11	18	ns

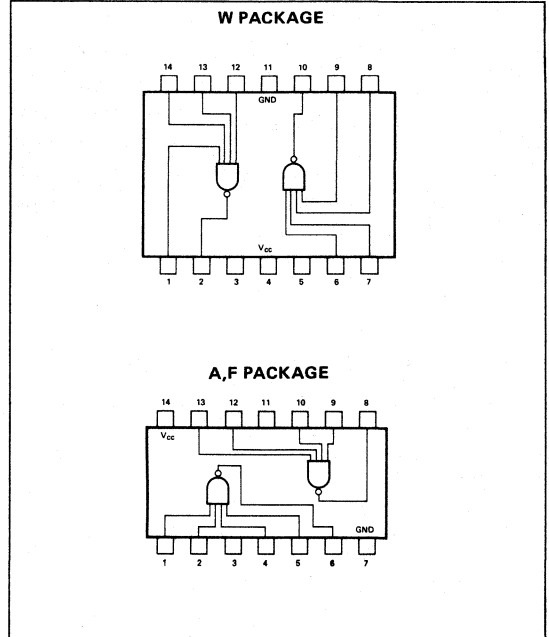
S5440—A,F,W • N7440—A,F

DIGITAL 54/74 TTL SERIES

### SCHEMATIC (each gate)



### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5440 Circuits	4.5	5	5.5	V
N7440 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			30	
Operating Free-Air Temperature Range, $T_A$ : S5440 Circuits	-55	25	125	°C
N7440 Circuits	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$	2		V	
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$ ,		0.8	V	
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -1.2\text{mA}$	2.4	3.3	V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 48\text{mA}$		0.28	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-1.6	mA	
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$		40	1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$ ,	S5440 N7440	-20 -18	-70 -70	mA mA

**SIGNETICS DUAL 4-INPUT POSITIVE NAND BUFFER ■ S5440, N7440**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		17	27	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		4	6.8	mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5V, T_A = 25^\circ\text{C}, N = 30$**

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15\text{pF},$	$R_L = 133\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15\text{pF},$	$R_L = 133\Omega$		13	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ\text{C}.$

† Not more than one output should be shorted at a time.

N7441B

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The N7441B Nixie\* Decoder/Driver is a one-out-of-ten decoder which has been designed to provide the necessary high voltage characteristics required for driving gas-filled cold-cathode indicator tubes.

It may also be utilized in driving relays or other high voltage interface circuitry. The element is designed using TTL techniques and is therefore completely compatible with DTL and TTL elements.

The specially designed output drivers provide the necessary stable output state. There are no input codes where all outputs are "off" or where more than one output can be turned "on".

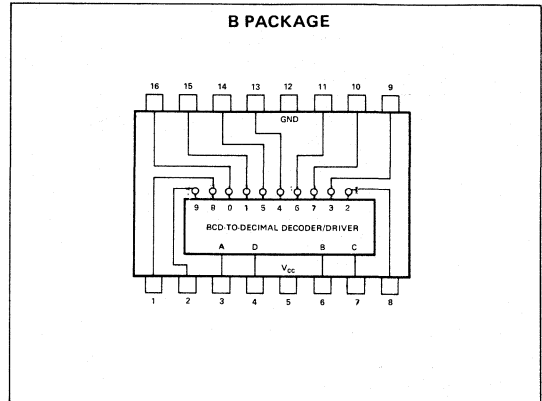
### RECOMMENDED OPERATING CONDITIONS

Supply Voltage $V_{CC}$ (See Note 1)	4.75 to 5.25V
Maximum Voltage on any Output	70V

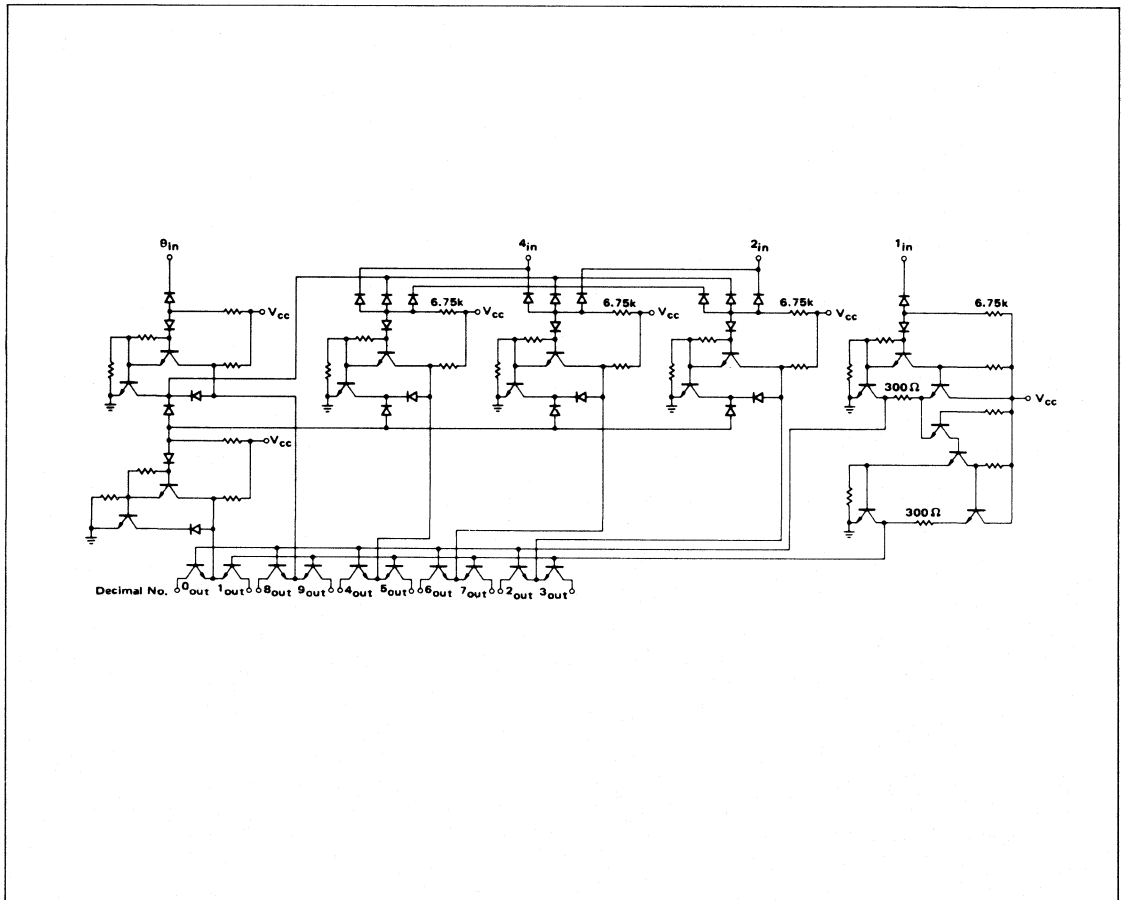
### NOTE:

1. These voltage values are with respect to network ground terminal.

### PIN CONFIGURATION

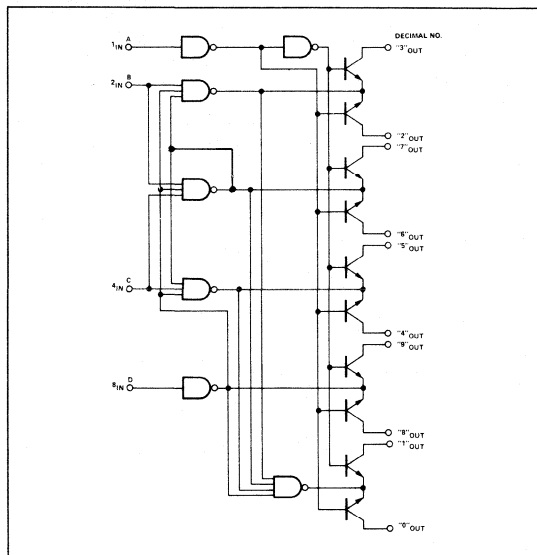


### SCHEMATIC DIAGRAM



# SIGNETICS BCD-TO-DECIMAL DECODER/DRIVER ■ N7441

## LOGIC DIAGRAM



## TRUTH TABLE

INPUT				OUTPUT ON†
D	C	B	A	
0	0	0	0	0
0	0	0	1	1
0	0	1	0	2
0	0	1	1	3
0	1	0	0	4
0	1	0	1	5
0	1	1	0	6
0	1	1	1	7
1	0	0	0	8
1	0	0	1	9

† All other inputs are off.

ELECTRICAL CHARACTERISTICS,  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ , unless otherwise noted.

PARAMETER		TEST CONDITIONS	MIN	TYP*	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage	$V_{CC} = 4.75\text{V}$	2			V
$V_{in(0)}$	Logical 0 input voltage	$V_{CC} = 4.75\text{V}$			0.8	V
$V_{on}$	On-state output voltage	$V_{CC} = 4.75\text{V}$ , $I_{on} = 7\text{mA}$			2.5	V
$I_{off}$	Off-state reverse current	$V_{CC} = 5.25\text{V}$ , $V_{out} = 55\text{V}$ $V_{CC} = 5.25\text{V}$ , $V_{out} = 70\text{V}$			50 2	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at B, C, or D	$V_{CC} = 5.25\text{V}$ , $V_{CC} = 5.25\text{V}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at A	$V_{CC} = 5.25\text{V}$ , $V_{CC} = 5.25\text{V}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA
$I_{in(0)}$	Logical 0 level input current at B, C, or D	$V_{CC} = 5.25\text{V}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$	Logical 0 level input current at A	$V_{CC} = 5.25\text{V}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{CC}$	Supply current	$V_{CC} = 5.25\text{V}$		21	42	mA

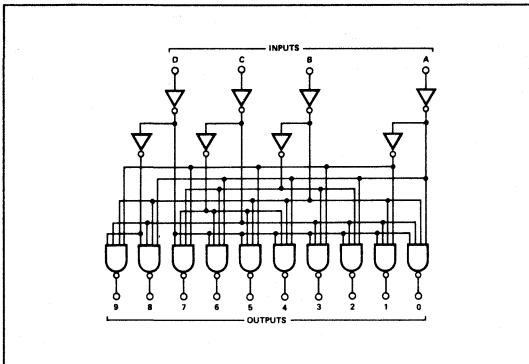
\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

\*Trademark Burroughs Corporation.

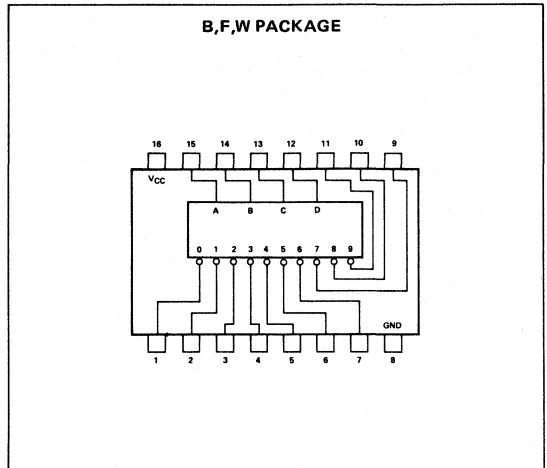
### DESCRIPTION

The 54/7442 BCD-to-Decimal Decoder is a TTL MSI array utilized in decoding and logic conversion applications. The 54/7442 decodes a four bit BCD number to one of ten outputs.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

S5442/N7442 BCD INPUT				ALL TYPES DECIMAL OUTPUT									
D	C	B	A	0	1	2	3	4	5	6	7	8	9
0	0	0	0	1	1	1	1	1	1	1	1	1	1
0	0	0	1	1	1	1	1	1	1	1	1	1	1
0	0	1	0	1	1	1	1	1	1	1	1	1	1
0	0	1	1	1	1	1	1	1	1	1	1	1	1
0	1	0	0	1	1	1	1	1	1	1	1	1	1
0	1	0	1	1	1	1	1	1	1	1	1	1	1
0	1	1	0	1	1	1	1	1	1	1	1	1	1
0	1	1	1	1	1	1	1	1	1	1	1	1	1
1	0	0	0	1	1	1	1	1	1	1	1	1	1
1	0	0	1	1	1	1	1	1	1	1	1	1	1
1	0	1	0	1	1	1	1	1	1	1	1	1	1
1	0	1	1	1	1	1	1	1	1	1	1	1	1
1	1	0	0	1	1	1	1	1	1	1	1	1	1
1	1	0	1	1	1	1	1	1	1	1	1	1	1
1	1	1	0	1	1	1	1	1	1	1	1	1	1
1	1	1	1	1	1	1	1	1	1	1	1	1	1
1	1	1	1	1	1	1	1	1	1	1	1	1	1

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5442 Circuits	4.5	5	5.5	V
N7442 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	



**SIGNETICS BCD-TO-DECIMAL DECODER ■ S5442, N7442**

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V,$ $I_{load} = -400\mu A$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V,$ $I_{sink} = 16mA$			0.4	V
$I_{in(1)}$ Logical 1 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 2.4V$			40	$\mu A$
	$V_{CC} = \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{in(0)}$ Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			-1.6	mA
$I_{OS}$ Short-circuit output current †	$V_{CC} = \text{MAX},$ S5442	-20		-55	mA
	N7442	-18		-55	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ S5442		28	41	mA
	N7442		28	56	mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5V, T_A = 25^\circ C, N = 10$**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$ Propagation delay time to logical 0 level through two logic levels	$C_L = 15pF, R_L = 400\Omega$	10	22	30	ns
$t_{pd0}$ Propagation delay time to logical 0 level through three logic levels	$C_L = 15pF, R_L = 400\Omega$		23	35	ns
$t_{pd1}$ Propagation delay time to logical 1 level through two logic levels	$C_L = 15pF, R_L = 400\Omega$	10	17	25	ns
$t_{pd1}$ Propagation delay time to logical 1 level through three logic levels	$C_L = 15pF, R_L = 400\Omega$		26	35	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

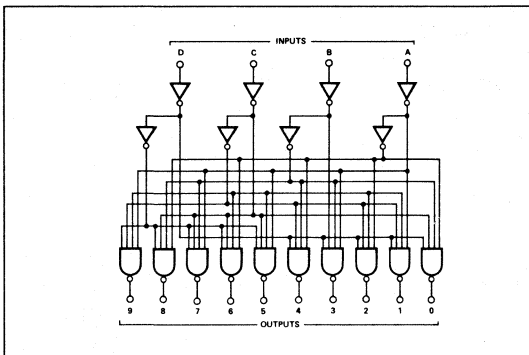
S5443-B,F,W • N7443-B

DIGITAL 54/74 TTL SERIES

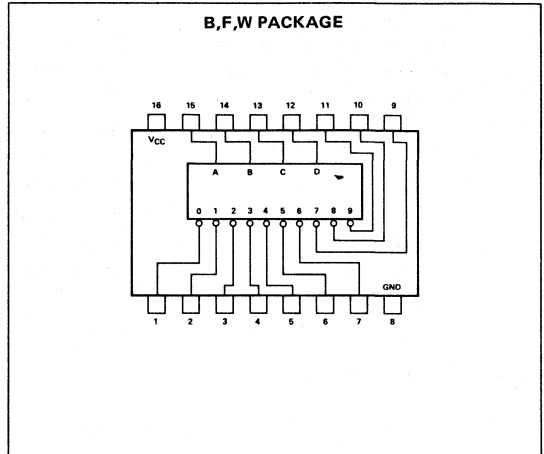
### DESCRIPTION

The 54/7443 Excess 3 Code to Decimal Decoder is a TTL MSI array utilized in decoding and logic conversion application. The 54/7443 decodes excess 3 code numbers to one of ten outputs.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

S5443/N7443 EXCESS INPUT				ALL TYPES DECIMAL OUTPUT									
D	C	B	A	0	1	2	3	4	5	6	7	8	9
0	0	1	1	1	1	1	1	1	1	1	1	1	1
0	1	0	0	1	0	1	1	1	1	1	1	1	1
0	1	0	1	1	1	0	1	1	1	1	1	1	1
0	1	1	0	1	1	1	0	1	1	1	1	1	1
1	0	0	0	1	1	1	1	0	1	1	1	1	1
1	0	0	1	1	1	1	1	1	0	1	1	1	1
1	0	1	0	1	1	1	1	1	1	0	1	1	1
1	0	1	1	1	1	1	1	1	1	1	0	1	1
1	1	0	0	1	1	1	1	1	1	1	1	1	0
1	1	0	1	1	1	1	1	1	1	1	1	1	1
1	1	1	0	1	1	1	1	1	1	1	1	1	1
1	1	1	1	1	1	1	1	1	1	1	1	1	1
0	0	0	0	0	0	0	0	0	0	0	0	0	0
0	0	0	1	0	0	0	0	0	0	0	0	0	0
0	0	1	0	0	0	0	0	0	0	0	0	0	0

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5443 Circuits	4.5	5	5.5	V
N7443 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	

## SIGNETICS EXCESS 3-TO-DECIMAL DECODER ■ S5443, N7443

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $V_{in(1)} = 2\text{V}$ , $V_{in(0)} = 0.8\text{V}$ , $I_{load} = -400\ \mu\text{A}$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $V_{in(1)} = 2\text{V}$ , $V_{in(0)} = 0.8\text{V}$ , $I_{sink} = 16\text{mA}$			0.4	V
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{OS}$	Short-circuit output current †	$V_{CC} = \text{MAX}$ , S5443 N7443	-20 -18		-55 -55	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ , S5443 N7443		28 28	41 56	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level through two logic levels	$C_L = 15\text{pF}$ ,	$R_L = 400\ \Omega$	10	22	30	ns
$t_{pd0}$	Propagation delay time to logical 0 level through three logic levels	$C_L = 15\text{pF}$ ,	$R_L = 400\ \Omega$		23	35	ns
$t_{pd1}$	Propagation delay time to logical 1 level through two logic levels	$C_L = 15\text{pF}$ ,	$R_L = 400\ \Omega$	10	17	25	ns
$t_{pd1}$	Propagation delay time to logical 1 level through three logic levels	$C_L = 15\text{pF}$ ,	$R_L = 400\ \Omega$		26	35	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions of the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

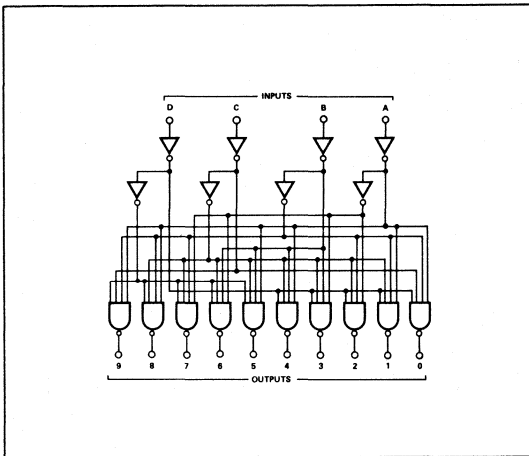
S5444-B,W • N7444-B,F

DIGITAL 54/74 TTL SERIES

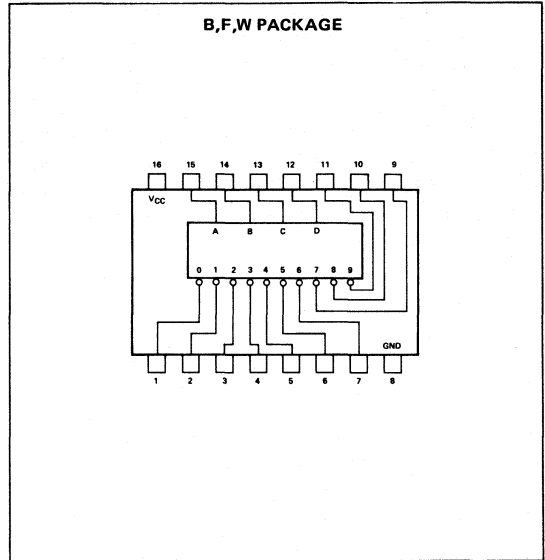
### DESCRIPTION

The 54/7444 Excess-3-Gray Code to Decimal Decoder is a TTL MSI array utilized in decoding and logic conversion applications. The 54/7444 decodes excess three gray code to one of ten outputs.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

S5444/N7444 EXCESS 3 GRAY INPUT				ALL TYPES DECIMAL OUTPUT									
D	C	B	A	0	1	2	3	4	5	6	7	8	9
0	0	1	0	0	1	1	1	1	1	1	1	1	1
0	1	1	0	1	0	1	1	1	1	1	1	1	1
0	1	1	1	1	1	0	1	1	1	1	1	1	1
0	1	0	1	1	1	1	0	1	1	1	1	1	1
0	1	0	0	1	1	1	1	0	1	1	1	1	1
1	1	0	1	1	1	1	1	1	0	1	1	1	1
1	1	1	1	1	1	1	1	1	1	0	1	1	1
1	1	1	0	1	1	1	1	1	1	1	0	1	1
1	0	1	0	1	1	1	1	1	1	1	1	1	0
1	0	1	1	1	1	1	1	1	1	1	1	1	1
1	0	0	1	1	1	1	1	1	1	1	1	1	1
1	0	0	0	1	1	1	1	1	1	1	1	1	1
1	0	0	0	0	1	1	1	1	1	1	1	1	1
0	0	0	0	0	0	0	0	0	0	0	0	0	0
0	0	0	1	1	1	1	1	1	1	1	1	1	1
0	0	1	1	1	1	1	1	1	1	1	1	1	1

### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5444 Circuits	4.5	5	5.5	V
N7444 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	

## SIGNETICS EXCESS 3-GRAY-TO-DECIMAL DECODER ■ S5444, N7444

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V, I_{load} = -400\mu A$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V, I_{sink} = 16mA$			0.4	V
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 2.4V$			40	$\mu A$
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			-1.6	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX},$ S5444 N7444	-20 -18		-55 -55	mA mA
$I_{CC}$	Supply Current	$V_{CC} = \text{MAX},$ S5444 N7444		28 28	41 56	mA mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level through two logic levels	$C_L = 15pF, R_L = 400\Omega$	10	22	30	ns
$t_{pd0}$	Propagation delay time to logical 0 level through three logic levels	$C_L = 15pF, R_L = 400\Omega$		23	35	ns
$t_{pd1}$	Propagation delay time to logical 1 level through two logic levels	$C_L = 15pF, R_L = 400\Omega$	10	17	25	ns
$t_{pd1}$	Propagation delay time to logical 1 level through three logic levels	$C_L = 15pF, R_L = 400\Omega$		26	35	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

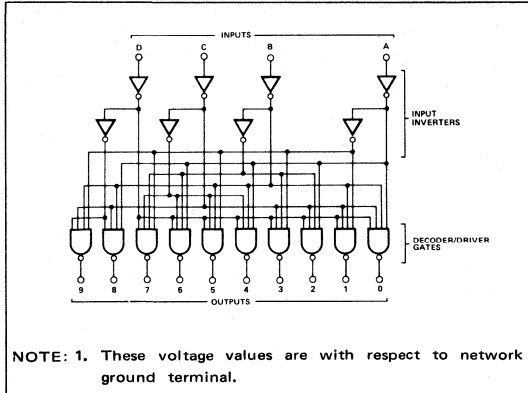
S5445-F,W • S54145-F,W • N7445-B • N74145-B

DIGITAL 54/74 TTL SERIES

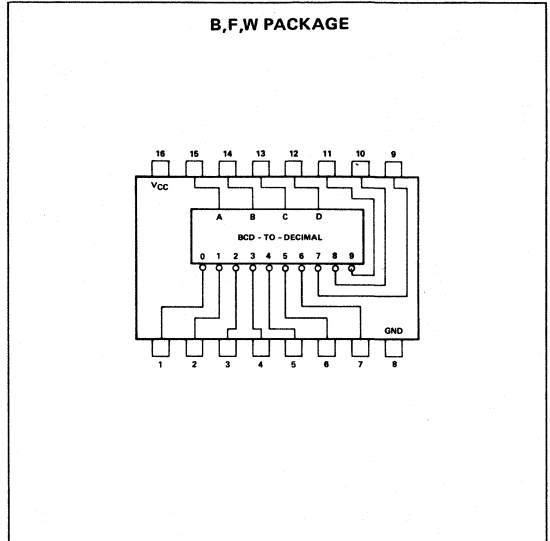
### DESCRIPTION

The 54/7445 and 54/74145 BCD-to-Decimal Decoder/Driver is a TTL MSI array. It features standard TTL inputs and high voltage, high current (80mA) outputs. The 54/7445 minimum output breakdown is 30 volts and the 54/74145 minimum output breakdown is 15 volts.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

INPUTS				OUTPUTS									
D	C	B	A	0	1	2	3	4	5	6	7	8	9
0	0	0	0	1	0	0	0	0	0	0	0	0	0
0	0	0	1	0	1	0	0	0	0	0	0	0	0
0	0	1	0	0	0	1	0	0	0	0	0	0	0
0	0	1	1	0	0	0	1	0	0	0	0	0	0
0	1	0	0	0	1	0	0	1	0	0	0	0	0
0	1	0	1	0	0	0	1	1	0	0	0	0	0
0	1	1	0	0	0	1	0	0	1	0	0	0	0
0	1	1	1	0	0	0	1	1	1	0	0	0	0
1	0	0	0	0	1	1	1	1	1	0	1	0	1
1	0	0	1	0	1	1	1	1	1	1	1	0	1
1	0	1	0	0	1	1	1	1	1	1	1	1	0
1	0	1	1	0	1	1	1	1	1	1	1	1	1
1	1	0	0	0	1	1	1	1	1	1	1	1	1
1	1	0	1	0	1	1	1	1	1	1	1	1	1
1	1	1	0	0	1	1	1	1	1	1	1	1	1
1	1	1	1	0	1	1	1	1	1	1	1	1	1
1	1	1	1	1	0	1	1	1	1	1	1	1	1
1	1	1	1	0	1	1	1	1	1	1	1	1	1
1	1	1	1	1	1	1	1	1	1	1	1	1	1

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage V <sub>CC</sub> (See Note 1): S5445, S54145 Circuits	4.5	5	5.5	V
N7445, N74145 Circuits	4.75	5	5.25	V
Voltage on any Output S5445, N7445 Circuits			30	V
S54145, N74145 Circuits			15	V

# SIGNETICS BCD-TO-DECIMAL DECODER/DRIVER ■ S5445, S54145, N7445, N74145

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{on}$	On-state output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 80\text{mA}$ $V_{CC} = \text{MIN}, I_{\text{sink}} = 20\text{mA}$		0.5	0.9	V
$V_{off}$	Off-state output voltage (S5445 or N7445)	$V_{CC} = \text{MAX}, I_{\text{off}} = 250\mu\text{A}$	30			V
$V_{off}$	Off-state output voltage (S54145 or N74145)	$V_{CC} = \text{MAX}, I_{\text{off}} = 250\mu\text{A}$	15			V
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			40	$\mu\text{A}$
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-1.6	$\text{mA}$
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ S5445, S54145 N7445, N74145		43	62	$\text{mA}$
				43	70	$\text{mA}$

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd1}$	Propagation delay time logical 1 level	$C_L = 15\text{pF}, R_L = 100\ \Omega$			50	ns
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15\text{pF}, R_L = 100\ \Omega$			50	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

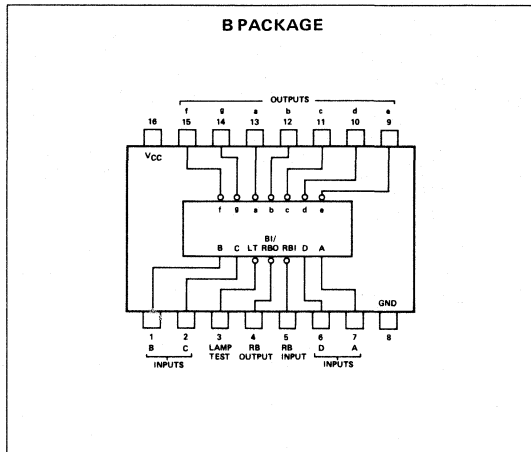
### DESCRIPTION

The 7446 and 7447 BCD-to-Seven Segment Decoder/Driver are TTL monolithic devices consisting of the necessary logic to decode a BCD code to seven segment readout plus selected signs.

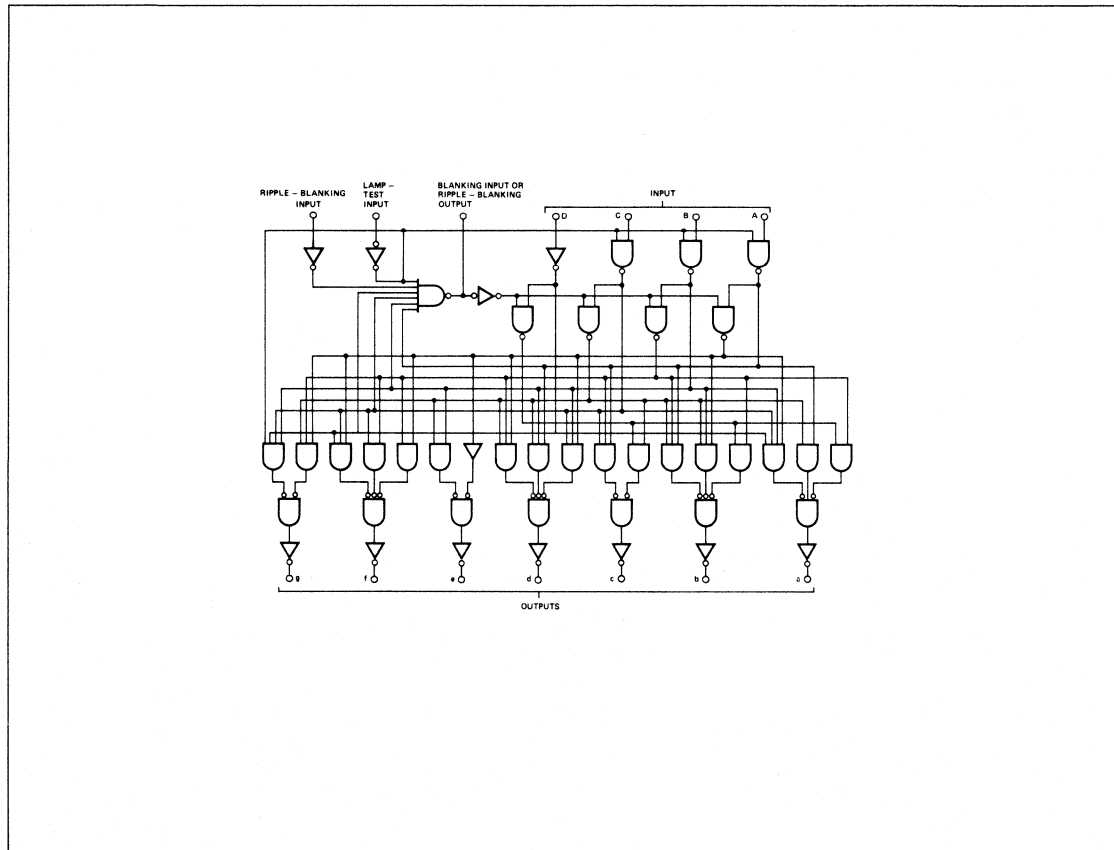
Incorporated in this device is a blanking circuit allowing leading and trailing zero suppression. Also included is a lamp test control to turn on all segments.

The 7446 and 7447 provide bare collector output transistors for directly driving lamps. The output transistor breakdown of the 7446 is 30 volts and the 7447 is 15 volts.

### PIN CONFIGURATION



### LOGIC DIAGRAM





# SIGNETICS BCD-TO-SEVEN SEGMENT DECODER/DRIVER ■ N7446, N7447

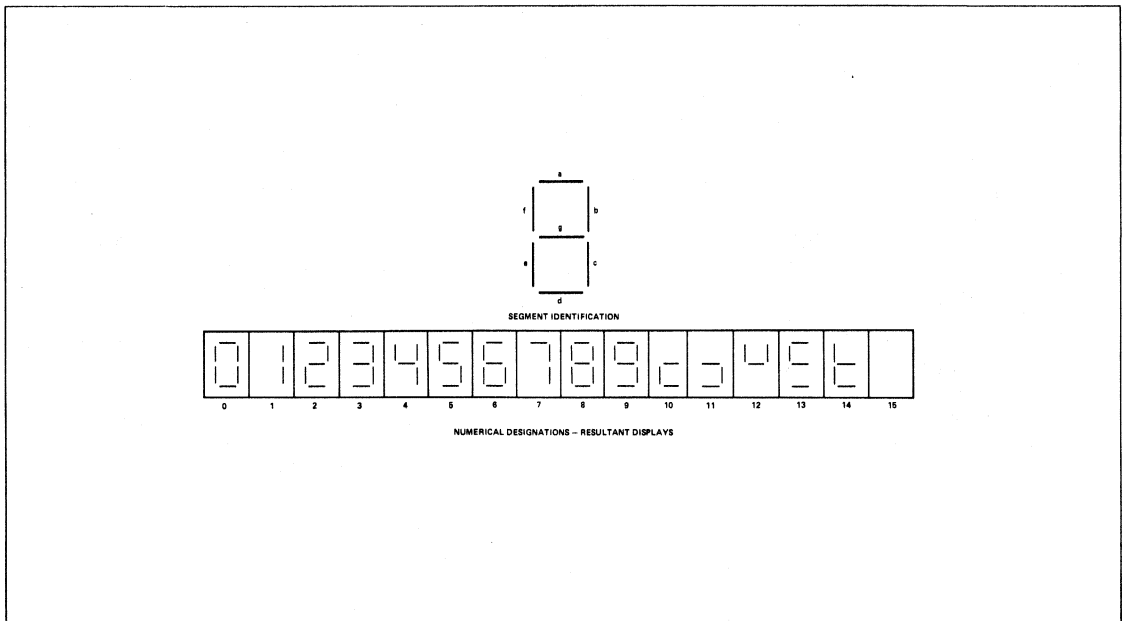
TRUTH TABLE

DECIMAL OR FUNCTION	INPUTS							OUTPUTS							NOTE
	LT	RBI	D	C	B	A	BI/RBO	a	b	c	d	e	f	g	
0	1	1	0	0	0	0	1	0	0	0	0	0	0	1	1
1	1	x	0	0	0	1	1	1	0	0	1	1	1	1	1
2	1	x	0	0	1	0	1	0	0	1	0	0	1	0	0
3	1	x	0	0	1	1	1	0	0	0	0	1	1	0	0
4	1	x	0	1	0	0	1	1	0	0	1	1	0	0	0
5	1	x	0	1	0	1	1	0	1	0	0	0	1	0	0
6	1	x	0	1	1	0	1	1	1	0	0	0	0	0	0
7	1	x	0	1	1	1	1	0	0	0	1	1	1	1	1
8	1	x	1	0	0	0	1	0	0	0	0	0	0	0	0
9	1	x	1	0	0	1	1	0	0	0	1	1	0	0	0
10	1	x	1	0	1	0	1	1	1	1	0	0	1	0	0
11	1	x	1	0	1	1	1	1	1	0	0	1	1	0	0
12	1	x	1	1	0	0	1	1	0	1	1	1	0	0	0
13	1	x	1	1	0	1	1	0	1	1	0	1	0	0	0
14	1	x	1	1	1	0	1	1	1	1	0	0	0	0	0
15	1	x	1	1	1	1	1	1	1	1	1	1	1	1	1
BI	x	x	x	x	x	x	0	1	1	1	1	1	1	1	2
RBI	1	0	0	0	0	0	0	1	1	1	1	1	1	1	3
LT	0	x	x	x	x	x	1	0	0	0	0	0	0	0	4

NOTES:

1. BI/BRO is wire-OR logic serving as blanking input (BI) and/or ripple-blanking output (RBO). The blanking input must be open or held at a logical 1 when output functions 0 through 15 are desired and ripple-blanking input (RBI) must be open or at a logical 1 during the decimal 0 input. X = input may be high or low.
2. When a logical 0 is applied to the blanking input (forced condition) all segment outputs go to a logical 1 regardless of the state of any other input condition.
3. When ripple-blanking input (RBI) is at a logical 0 and A = B = C = D = logical 0, all segment outputs go to a logical 1 and the ripple-blanking output goes to a logical 0 (response condition).
4. When blanking input/ripple-blanking output is open or held at a logical 1, and a logical 0 is applied to lamp-test input, all segment outputs go to a logical 0.

SEGMENT IDENTIFICATION



# SIGNETICS BCD-TO-SEVEN SEGMENT DECODER/DRIVER ■ N7446, N7447

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ (See Note 1): N7446, N7447 Circuits	4.75	5	5.25	V
Continuous Voltage at Outputs a through g: N7446 Circuits			30	V
N7447 Circuits			15	V
Normalized Fan-Out From Outputs a through g to Series 54/74 loads: N7446, N7447 Circuits			12	
Normalized Fan-Out From BI/RBO Node to Series 54/74 loads: N7446, N7447 Circuits			5	
Output Sink Current, $I_{sink}$ : N7446, N7447 Outputs a through g			20	mA
N7446, N7447, BI/RBO Node			8	mA

### NOTES:

1. These voltage values are with respect to network ground terminal.
2. Input voltage must be zero or positive with respect to network ground terminal.
3. This rating applies when the output is off.

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any point	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input	$V_{CC} = \text{MIN}$			0.8	V
$V_{on}$ On-state output voltage at outputs a through g	$V_{CC} = \text{MIN}, I_{sink} = 40\text{mA}$		0.27	0.4	V
$V_{out(0)}$ Logical 0 output voltage at BI/RBO node	$V_{CC} = \text{MIN}, I_{sink} = 8\text{mA}$		0.3	0.4	V
$V_{off}$ Off-state output voltage at outputs a through g (S5446 and N7446 only)	$V_{CC} = \text{MAX}, I_{off} = 250 \text{ A}$	30			V
$V_{off}$ Off-state output voltage at outputs a through g (S5447 and N7447 only)	$V_{CC} = \text{MAX}, I_{off} = 250 \text{ A}$	15			V
$V_{out(1)}$ Logical 1 output voltage at BI/RBO node	$V_{CC} = \text{MIN}, I_{load} = 200 \text{ A}$	2.4	3.7		V
$I_{in(0)}$ Logical 0 level input current at any input except BI/RBO node	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at BI/RBO node	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-4.2	mA
$I_{in(1)}$ Logical 1 level input current at any input except BI/RBO node	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{OS}$ Short-circuit output current at BI/RBO node	$V_{CC} = \text{MAX}$			-4	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ N7446, N7447		53	90	mA

# SIGNETICS BCD-TO-SEVEN SEGMENT DECODER/DRIVER ■ N7446, N7447

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd1}$	Propagation delay time to logical 1 level from A input to any output	$C_L = 15pF$ ,	$R_L = 280 \Omega$			100	ns
$t_{pd0}$	Propagation delay time to logical 0 level from A input to any output	$C_L = 15pF$ ,	$R_L = 280 \Omega$			100	ns
$t_{pd1}$	Propagation delay time to logical 1 level from RBI input to any output	$C_L = 15pF$ ,	$R_L = 280 \Omega$			100	ns
$t_{pd0}$	Propagation delay time to logical 0 level from RBI input to any output	$C_L = 15pF$ ,	$R_L = 280 \Omega$			100	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

N7448-B

DIGITAL 54/74 TTL SERIES

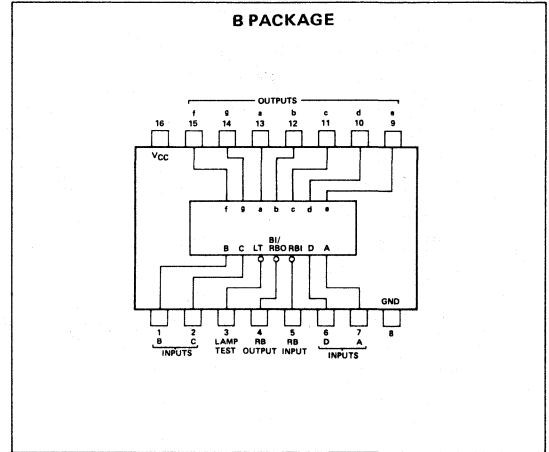
### DESCRIPTION

The 7448 BCD-to-Seven Segment Decoder/Driver is a TTL monolithic device consisting of the necessary logic to decode a BCD code to seven segment readout plus selected signs.

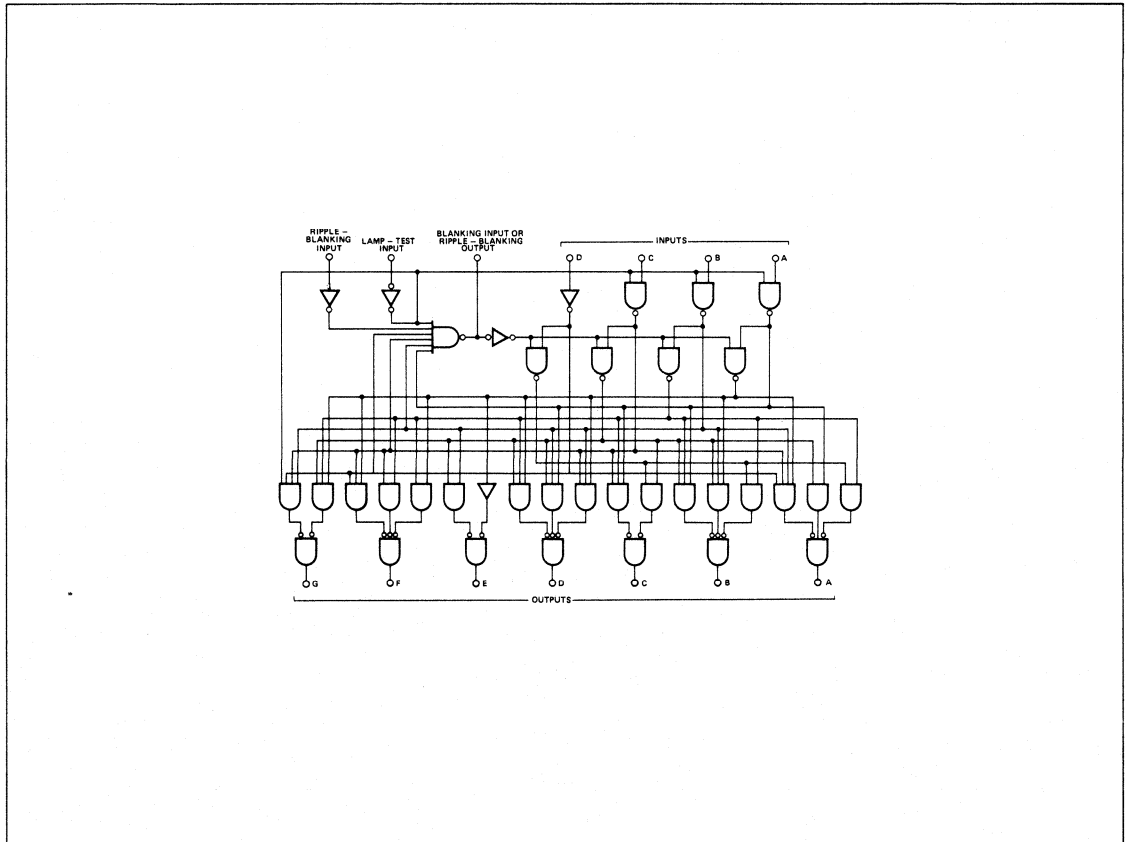
Incorporated in this device is a blanking circuit allowing leading and trailing zero suppression. Also included is a lamp test control to turn on all segments.

The 7448 has resistor pull up on the outputs to provide source current to drive interface elements.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



# SIGNETICS BCD-TO-SEVEN SEGMENT DECODER/DRIVER ■ N7448

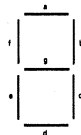
## TRUTH TABLE

FUNCTION	INPUTS						OUTPUTS							NOTE	
	LT	RBI	D	C	B	A	BI/RBO	a	b	c	d	e	f		g
0	1	1	0	0	0	0	1	1	1	1	1	1	1	0	1
1	1	x	0	0	0	1	1	0	1	1	0	0	0	0	1
2	1	x	0	0	1	0	1	1	1	0	1	1	0	0	1
3	1	x	0	0	1	1	1	1	1	1	1	0	0	1	1
4	1	x	0	1	0	0	1	0	1	1	0	0	1	1	1
5	1	x	0	1	0	1	1	1	0	1	1	0	1	1	1
6	1	x	0	1	1	0	1	0	0	1	1	1	1	1	1
7	1	x	0	1	1	1	1	1	1	1	0	0	0	0	0
8	1	x	1	0	0	0	1	1	1	1	1	1	1	1	1
9	1	x	1	0	0	1	1	1	1	1	0	0	1	1	1
10	1	x	1	0	1	0	1	0	0	0	1	1	0	1	1
11	1	x	1	0	1	1	1	0	0	1	1	0	0	0	1
12	1	x	1	1	0	0	1	0	1	0	0	0	1	1	1
13	1	x	1	1	0	1	1	1	0	0	1	0	1	1	1
14	1	x	1	1	1	0	1	0	0	0	1	1	1	1	1
15	1	x	1	1	1	1	1	0	0	0	0	0	0	0	0
BI	x	x	x	x	x	x	0	0	0	0	0	0	0	0	2
RBI	1	0	0	0	0	0	0	0	0	0	0	0	0	0	3
LT	0	x	x	x	x	x	1	1	1	1	1	1	1	1	4

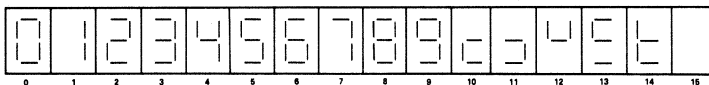
### NOTES:

1. BI/RBO is wire-OR logic serving as blanking input (BI) and/or ripple-blanking output (RBO). The blanking input must be open or held at a logical 1 when output functions 0 through 15 are desired and ripple-blanking input (RBI) must be open or at a logical 1 during the decimal 0 input. X = input may be high or low.
2. When a logical 0 is applied to the blanking input (forced condition) all segment outputs go to a logical 1 regardless of the state of any other input condition.
3. When ripple-blanking input (RBI) is at a logical 0 and A = B = C = D = logical 0, all segment outputs go to a logical 1 and the ripple-blanking output goes to a logical 0 (response condition).
4. When blanking input/ripple-blanking output is open or held at a logical 1, and a logical 0 is applied to lamp-test input, all segment outputs go to a logical 1.

### SEGMENT IDENTIFICATION



SEGMENT IDENTIFICATION



NUMERICAL DESIGNATIONS - RESULTANT DISPLAYS

# SIGNETICS BCD-TO-SEVEN SEGMENT DECODER/DRIVER ■ N7448

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ (See Note 1): N7448 Circuit	4.75	5	5.25	V
Normalized Fan-Out From Outputs a through g to Series 54/74 loads: N7448 Circuits			4	
Normalized Fan-Out From BI/RBO Node to Series 54/74 Loads: N7448 Circuits			5	
Output Sink Current, $I_{sink}$ : N7448 Outputs a through g N7448 BI/RBO Node			6.4 8	mA mA

### NOTES:

1. These voltage values are with respect to network ground terminal.
2. Input voltage must be zero or positive with respect to network ground terminal.
3. This rating applies when the output is off.

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(0)}$ Logical 0 output voltage at any output	$V_{CC} = \text{MIN}, I_{sink} = \text{MAX}$		0.27	0.4	V
$V_{out(1)}$ Logical 1 level output voltage at outputs a through g	$V_{CC} = \text{MIN}, I_{load} = -400 \mu\text{A}$	2.4	4.2		V
$V_{out(1)}$ Logical 1 level output at BI/RBO node	$V_{CC} = \text{MIN}, I_{load} = 200 \mu\text{A}$	2.4	3.7		V
$I_{load}$ Load current available at outputs a through g	$V_{CC} = \text{MIN}, V_{out} = 0.85\text{V}$	-1.3	-2		mA
$I_{in(0)}$ Logical 0 level input current of any input except BI/RBO node	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at BI/RBO node	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-4.2	mA
$I_{in(1)}$ Logical 1 level input current at any input except BI/RBO node	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			40	$\mu\text{A}$
	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
$I_{OS}$ Short-circuit output current at any output	$V_{CC} = \text{MAX}$			-4	mA
$I_{CC}$ Supply current	S5448		53	76	mA
	N7448		53	90	mA

## SIGNETICS BCD-TO-SEVEN SEGMENT DECODER/DRIVER ■ N7448

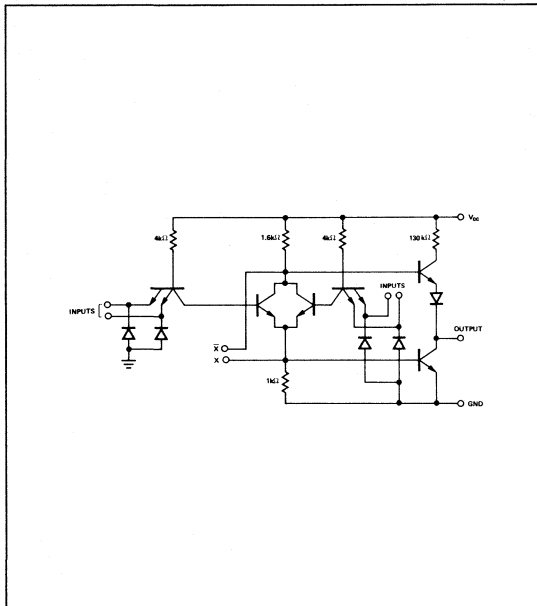
SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd1}$	Propagation delay time to logical 1 level from A input to any output	$C_L = 15pF$			100	ns
$t_{pd0}$	Propagation delay time to logical 0 level from A input to any output	$C_L = 15pF$			100	ns
$t_{pd1}$	Propagation delay time to logical 1 level from RBI input to any output	$C_L = 15pF$			100	ns
$t_{pd0}$	Propagation delay time to logical 0 level from RBI input to any output	$C_L = 15pF$			100	ns

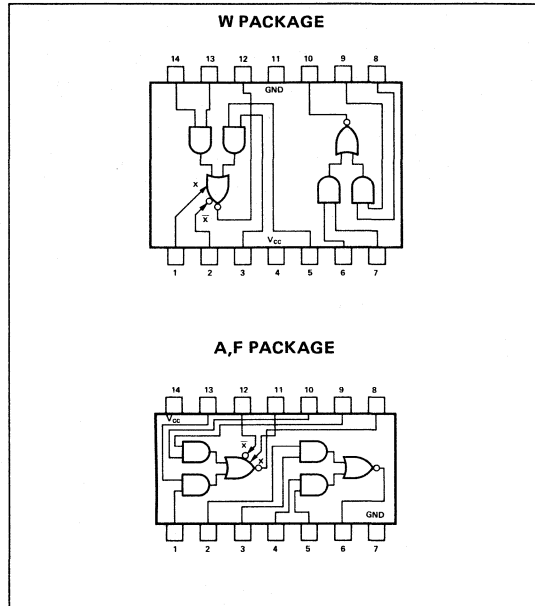
\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

#### SCHEMATIC (each gate)



#### PIN CONFIGURATIONS



#### NOTES:

1. Component values shown are nominal.
2. Both expander inputs are used simultaneously for expanding.
3. If expander is not used leave X and  $\bar{X}$  pins open.

4. Make no external connection to X and  $\bar{X}$  pins of the S5451 and N7451.
5. A total of four expander gates can be connected to the expander inputs.

#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5450, S5451 Circuits	4.5	5	5.5	V
N7450, N7451 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5450, S5451 Circuits	-55	25	125	$^{\circ}C$
N7450, N7451 Circuits	0	25	70	$^{\circ}C$

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at both input terminals of either AND section to ensure logical 0 at output	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Logical 0 input voltage required at one input terminal of each AND section to ensure logical 1 at output	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu A$ , $V_{in} = 0.8V$ ,	2.4	3.3		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16mA$ , $V_{in} = 2V$ ,		0.22	0.4	V



# SIGNETICS EXPANDABLE DUAL 2-WIDE 2-INPUT AND-OR-INVERT GATES ■ S5450/51, N7450/51

## ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$	$V_{in} = 0.4V$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$	$V_{in} = 2.4V$			40	$\mu A$
		$V_{CC} = \text{MAX},$	$V_{in} = 5.5V$			1	mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$	S5450, S5451 N7450, N7451	-20		-55	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		7.4	14	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		4	8	mA

## ELECTRICAL CHARACTERISTICS ( S5450 circuits ) using expander inputs, $V_{CC} = 4.5V, T_A = -55^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP**	MAX	UNIT
$I_X$	Expander current	$V_1 = 0.4V,$	$I_{sink} = 16mA$			2.9	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor (Q)	$I_{sink} = 16mA,$ $R_1 = 0$	$I_1 = 0.41mA,$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -400\mu A,$ $I_2 = -0.15mA$	$I_1 = 0.15mA,$	2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 16mA,$ $R_1 = 138\Omega$	$I_1 = 0.3mA,$		0.22	0.4	V

## ELECTRICAL CHARACTERISTICS (N7450 circuits) using expander inputs, $V_{CC} = 4.75V, T_A = 0^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP**	MAX	UNIT
$I_X$	Expander current	$V_1 = 0.4V,$	$I_{sink} = 16mA$			3.1	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor (Q)	$I_{sink} = 16mA,$ $R_1 = 0$	$I_1 = 0.62mA,$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -400\mu A,$ $I_2 = -270\mu A$	$I_1 = 270\mu A,$	2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 16mA,$ $R_1 = 130\Omega$	$I_1 = 0.43mA,$		0.22	0.4	V

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS*		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		13	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander inputs X and X are open.

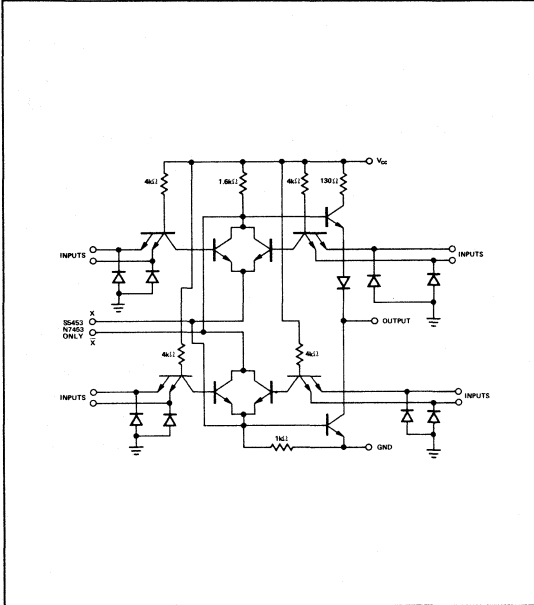
\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C.$

† Not more than one output should be shorted at a time.

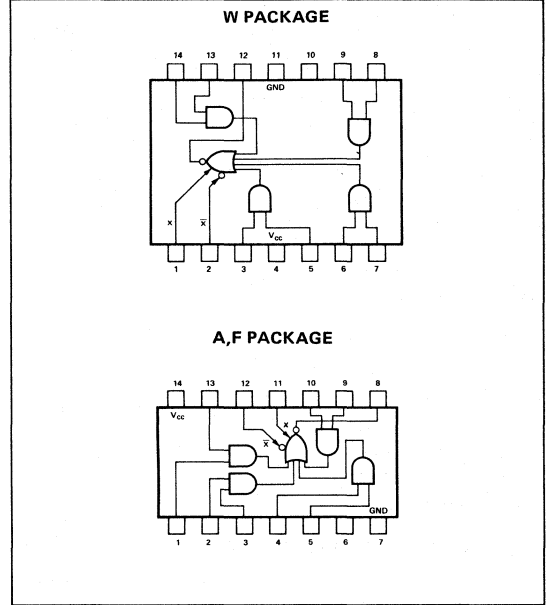
S5453-A,F,W • S5454-A,F,W • N7453-A,F • N7454-A,F

DIGITAL 54/74 TTL SERIES

#### SCHEMATIC DIAGRAM



#### PIN CONFIGURATIONS



#### NOTES:

1. Component values shown are nominal.
2. Both expander inputs are used simultaneously for expanding.
3. If expander is not used leave X and  $\bar{X}$  pins open.

4. Make no external connection to X and  $\bar{X}$  pins of the S5454 and N7454.
5. A total of four expander gates can be connected to the expander inputs.

#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5453, S5454 Circuits	4.5	5	5.5	V
N7453, N7454 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5453, S5454 Circuits	-55	25	125	°C
N7453, N7454 Circuits	0	25	70	°C

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at both input terminals of one AND section to ensure logical 0 level at output	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Logical 0 input voltage required at one input terminal of each AND section to ensure logical 1 level at output	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu A$ , $V_{in} = 0.8V$ ,	2.4	3.3		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16mA$ , $V_{in} = 2V$ ,		0.22	0.4	V

## SIGNETICS 4-WIDE 2-INPUT AND-OR-INVERT GATE ■ S5453, S5454, N7453, N7454

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$	$V_{in} = 0.4V$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$	$V_{in} = 2.4V$ $V_{in} = 5.5V$			40 1	$\mu A$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = 5.5V$	S5453, S5454 N7453, N7454	-20 -18		-55 -55	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 5V$		5.1	9.5	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		4	8	mA

### ELECTRICAL CHARACTERISTICS (S5453 circuits) using expander inputs, $V_{CC} = 4.5V, T_A = -55^\circ C$

PARAMETER		TEST CONDITIONS*			MIN	TYP**	MAX	UNIT
$I_X$	Expander current	$V_1 = 0.4V,$	$I_{sink} = 16mA$				2.9	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor (Q)	$I_{sink} = 16mA,$	$I_1 = 0.41mA,$	$R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -400\mu A,$ $I_2 = -0.15mA$	$I_1 = 0.15mA,$		2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 16mA,$	$I_1 = 0.3mA,$	$R_1 = 138\Omega$		0.22	0.4	V

### ELECTRICAL CHARACTERISTICS (N7453 circuits) using expander inputs, $V_{CC} = 4.75V, T_A = 0^\circ C$

PARAMETER		TEST CONDITIONS*			MIN	TYP**	MAX	UNIT
$I_X$	Expander current	$V_1 = 0.4V,$	$I_{sink} = 16mA$				3.1	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor (Q)	$I_{sink} = 16mA,$	$I_1 = 0.62mA,$	$R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -400\mu A,$ $I_2 = -270\mu A$	$I_1 = 270\mu A,$		2.4	3.3		V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 16mA,$	$I_1 = 0.43mA,$	$R_1 = 130\Omega$		0.22	0.4	V

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS*		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 15pF,$	$R_L = 400\Omega$		8	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 15pF,$	$R_L = 400\Omega$		13	22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander inputs X and  $\bar{X}$  are open.

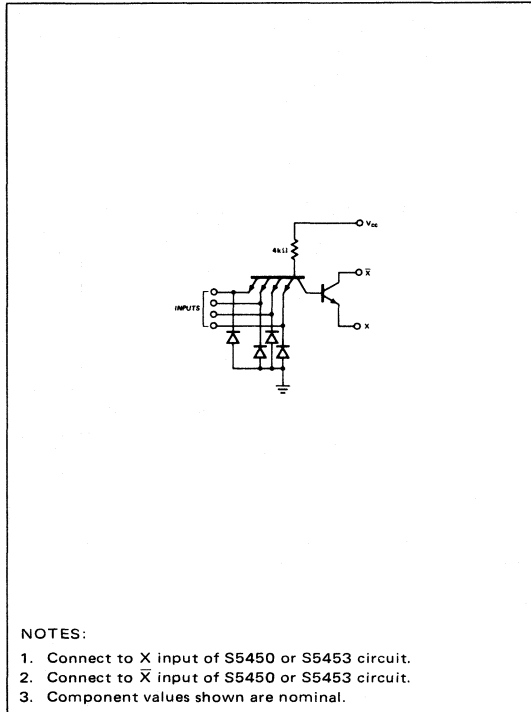
\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

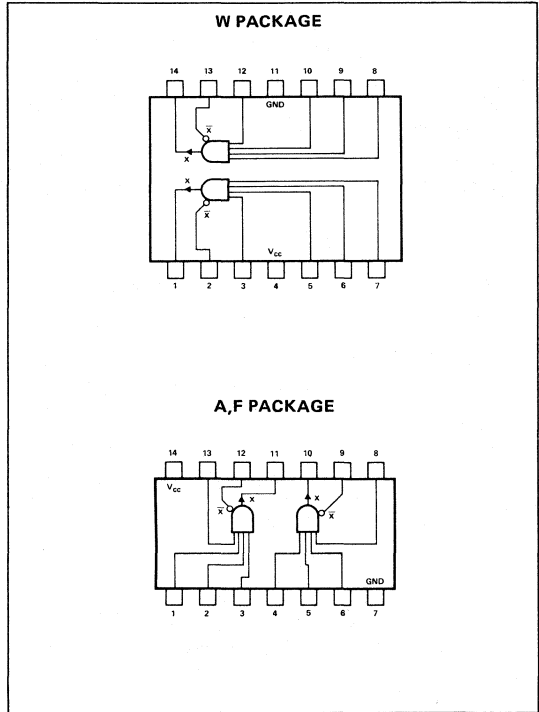
S5460-A,F,W

DIGITAL 54/74 TTL SERIES

**SCHEMATIC (each expander)**



**PIN CONFIGURATIONS**



**RECOMMENDED OPERATING CONDITIONS**

Supply Voltage $V_{CC}$	4.5V to 5.5V
Maximum number of expanders that may be fanned-in to one S5450 or one S5453 circuit	4

**ELECTRICAL CHARACTERISTICS (unless otherwise noted  $T_A = -55^\circ\text{C}$  to  $125^\circ\text{C}$ )**

PARAMETER	TEST CONDITIONS	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure output is in the on state $V_{CC} = 4.5V$	2			V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure output is in the off state $V_{CC} = 4.5V$			0.8	V
$V_{on}$	On-state output voltage $V_{CC} = 4.5V$ , $R = 1.1\text{ k}\Omega$ , $V_{in} = 2V$ , $T_A = -55^\circ\text{C}$			0.4	V
$I_{off}$	Off-state output current $V_{CC} = 4.5V$ , $R = 1.2\text{ k}\Omega$ , $V_{in} = 0.8V$ , $T_A = -55^\circ\text{C}$			150	$\mu\text{A}$
$I_{on}$	On-state output current $V_{CC} = 4.5V$ , $T_A = -55^\circ\text{C}$			-0.3	$\text{mA}$
$I_{in(0)}$	Logical 0 level input current (each input) $V_{CC} = 5.5V$ , $V_{in} = 0.4V$			-1.6	$\text{mA}$

## SIGNETICS DUAL 4-INPUT EXPANDER ■ S5460

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = 5.5V,$	$V_{in} = 2.4V$			40	$\mu A$
		$V_{CC} = 5.5V,$	$V_{in} = 5.5V$			1	mA
$I_{CC(on)}$	On-state supply current	$V_{CC} = 5.5V,$	$V_{in} = 5V,$		1.2	2.5	mA
$I_{CC(off)}$	Off-state supply current	$V_{CC} = 5.5V,$	$V_{in} = 0,$		2	4	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V,$ $T_A = 25^\circ C,$ $N = 10$

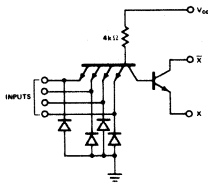
PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level (through S5450 or S5453 circuit)	$C_L = 15pF,$	$R_L = 400\Omega$		10	20	ns
$t_{pd1}$	Propagation delay time to logical 1 level (through S5450 or S5453 circuit)	$C_L = 15pF,$	$R_L = 400\Omega$		15	30	ns

\*\* All typical values are at  $V_{CC} = 5V,$   $T_A = 25^\circ C.$

N7460-A,F

DIGITAL 54/74 TTL SERIES

**SCHEMATIC (each expander)**

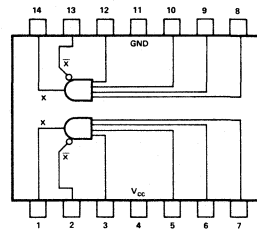


**NOTES:**

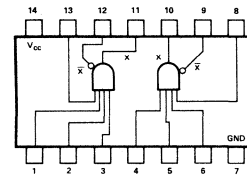
1. Connect to X input of N7450 or N7453 circuit.
2. Connect to  $\bar{X}$  input of N7450 or N7453 circuit.
3. Component values shown are nominal.

**PIN CONFIGURATIONS**

**W PACKAGE**



**A,F PACKAGE**



**RECOMMENDED OPERATING CONDITIONS**

Supply Voltage $V_{CC}$	4.75 to 5.25V
Maximum number of expanders that may be fanned-in to one N7450 or one N7453 circuit	4

**ELECTRICAL CHARACTERISTICS (unless otherwise noted  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ )**

PARAMETER	TEST CONDITIONS	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	$V_{CC} = 4.75V$	2			V
$V_{in(0)}$	$V_{CC} = 4.75V$			0.8	V
$V_{on}$	$V_{CC} = 4.75V$ , $R = 1.1\text{ k}\Omega$ , $V_{in} = 2V$ , $T_A = 0^\circ\text{C}$			0.4	V
$I_{off}$	$V_{CC} = 4.75V$ , $R = 1.2\text{ k}\Omega$ , $V_{in} = 0.8V$ , $T_A = 0^\circ\text{C}$			270	$\mu\text{A}$
$I_{on}$	$V_{CC} = 4.75V$ , $V_{in} = 2V$ , $V_1 = 1V$	-0.43			mA
$I_{in(0)}$	$V_{CC} = 5.25V$ , $V_{in} = 0.4V$			-1.6	mA
$I_{in(1)}$	$V_{CC} = 5.25V$ , $V_{in} = 2.4V$			40	$\mu\text{A}$
	$V_{CC} = 5.25V$ , $V_{in} = 5.5V$			1	mA

SIGNETICS DUAL 4-INPUT EXPANDER ■ N7460

ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{CC(on)}$	On-state supply current	$V_{CC} = 5.25V,$	$V_{in} = 5V,$	$V_1 = 0.85V$		1.2	2.5	mA
$I_{CC(off)}$	Off-state supply current	$V_{CC} = 5.25V,$	$V_{in} = 0$	$V_1 = 0.85V$		2	4	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level (through N7450 or N7453)	$C_L = 15pF,$	$R_L = 400\Omega$		10	20	ns
$t_{pd1}$	Propagation delay time to logical 1 level (through N7450 or N7453)	$C_L = 15pF,$	$R_L = 400\Omega$		15	30	ns

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C.$

#### DESCRIPTION

The S5470/N7470 is a monolithic, edge-triggered J-K flip-flop featuring gated inputs, direct clear and preset inputs, and complementary Q and  $\bar{Q}$  outputs. Input information is transferred to the outputs on the positive edge of the clock pulse.

Direct-coupled clock triggering occurs at a specific voltage level of the clock pulse; and after the clock input threshold voltage has been passed, the gated inputs are locked out.

The S5470/N7470 flip-flop is ideally suited for medium- and high-speed applications, and can be used for a significant saving in system power dissipation and package count where input gating is required.

#### TRUTH TABLE

##### LOGIC

$J_n$	$K_n$	$Q_{n+1}$	PRESET	CLEAR	Q
0	0	$Q_n$	0	0	†
1	0	1	1	0	0
0	1	0	0	1	1
1	1	$\bar{Q}_n$	1	1	Q

$$J = J_1 J_2 J^* \quad K = K_1 K_2 K^*$$

n is time prior to clock

n+1 is time following clock

† Both outputs in 0 state

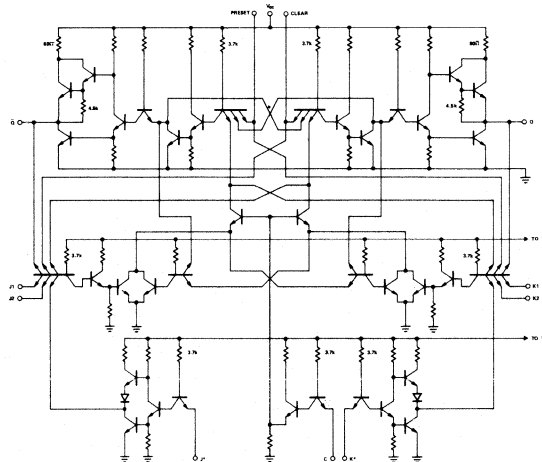
#### POSITIVE LOGIC

Low input to preset sets Q to logical 1

Low input to clear sets Q to logical 0

Preset or clear function can occur only when clock input is low.

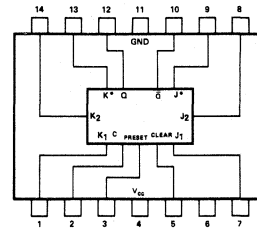
#### SCHEMATIC DIAGRAM



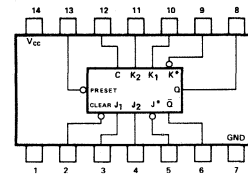
NOTE: Component values are typical.

#### PIN CONFIGURATIONS

##### W PACKAGE



##### A,F PACKAGE





RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5470 Circuits	4.5	5	5.5	V
N7470 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S5470 Circuits	-55	25	125	°C
N7470 Circuits	0	25	70	°C
Normalized Fanout from each Output, N			10	
Clock Pulse Transition Time to Logical 1 Level, $t_1$ (clock)	5		150	ns
Width of Clock Pulse, $t_p$ (clock)	20			ns
Width of Preset Pulse, $t_p$ (preset)	25			ns
Width of Clear Pulse, $t_p$ (clear)	25			ns

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	2.4	3.5		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$		0.22	0.4	V
$I_{in(0)}$ Logical 0 level input current at J1, J2, J*, K1, K2, K*, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at preset or clear	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(1)}$ Logical 1 level input current at J1, J2, J*, K1, K2, K*, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at preset or clear	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA
$I_{OS}$ Short circuit output current†	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	S5470 N7470	-20 -18	-75 -75	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 5\text{V}$		13	26	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{clock}$ Maximum clock frequency	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	15	35		MHz
$t_{setup}$ Minimum Input Setup time	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		10	20	ns
$t_{hold}$ Minimum input hold time	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		0	5	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clear or preset to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$			50	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear or preset to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$			50	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	27	50	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	18	50	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

#### DESCRIPTION

These J-K flip-flops are based on the master-slave principle and each has AND gate inputs for entry into the master section which are controlled by the clock pulse. The clock pulse also regulates the state of the coupling transistors which connect the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND gate inputs to master
3. Disable AND gate inputs
4. Transfer information from master to slave.

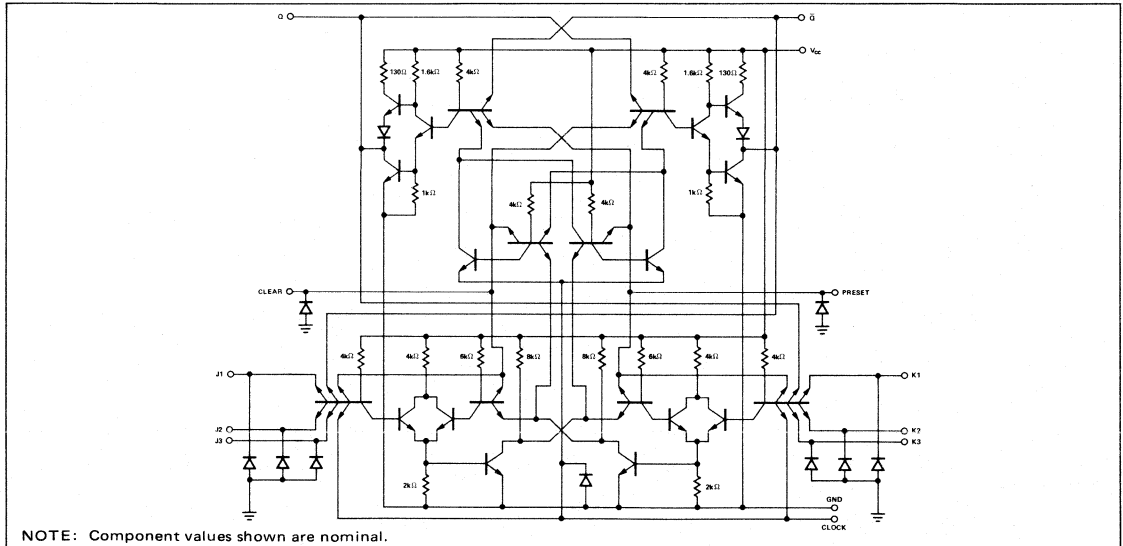
#### TRUTH TABLE

LOGIC		
$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

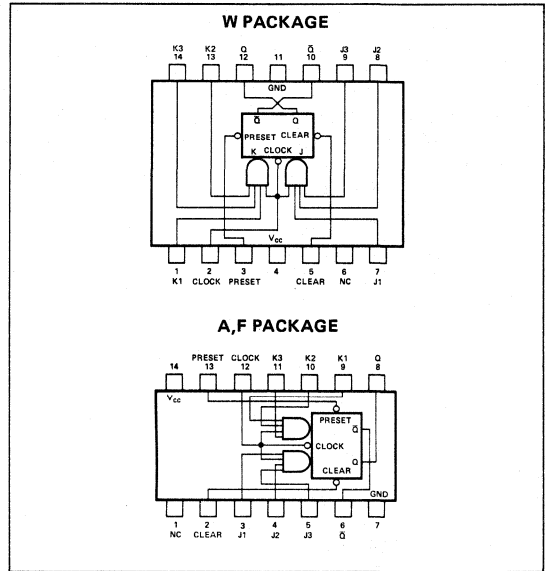
#### NOTES:

1.  $J = J1 \cdot J2 \cdot J3$
2.  $K = K1 \cdot K2 \cdot K3$
3.  $t_n$  = Bit time before clock pulse.
4.  $t_{n+1}$  = Bit time after clock pulse.
5. NC = No Internal Connection.

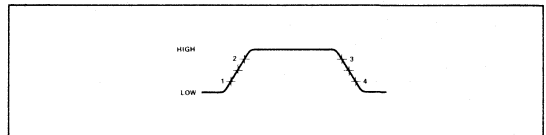
#### SCHEMATIC DIAGRAM



#### PIN CONFIGURATIONS



#### CLOCK WAVEFORM



# SIGNETICS J-K MASTER-SLAVE FLIP-FLOP ■ S5472, N7472

## RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5472 Circuits	4.5	5	5.5	V
N7472 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S5472 Circuits	-55	25	125	°C
N7472 Circuits	0	25	70	°C
Normalized Fan-Out From each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	20			ns
Width of Preset Pulse, $t_p(\text{preset})$	25			ns
Width of Clear Pulse, $t_p(\text{clear})$	25			ns
Input Setup Time, $t_{\text{setup}}$	$\geq t_p(\text{clock})$			
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal $V_{CC} = \text{MIN}$	2			V	
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal $V_{CC} = \text{MIN}$			0.8	V	
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}$ , $I_{\text{load}} = -400\mu\text{A}$	2.4	3.5		V	
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 16\text{mA}$		0.22	0.4	V	
$I_{in(0)}$	Logical 0 level input current at J1, J2, J3, K1, K2, or K3 $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA	
$I_{in(0)}$	Logical 0 level input current at preset, clear, or clock $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA	
$I_{in(1)}$	Logical 1 level input current at J1, J2, J3, K1, K2, or K3 $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA	
$I_{in(1)}$	Logical 1 level input current at preset, clear, or clock $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA	
$I_{OS}$	Short circuit output current† $V_{CC} = \text{MAX}$ , $V_{in} = 0$	S5472 N7472		-20 -18	mA	
$I_{CC}$	Supply current $V_{CC} = \text{MAX}$ , $V_{in} = 5\text{V}$			10	20	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$	Maximum clock frequency $C_L = 15\text{pF}$ , $R_L = 400\Omega$	15	20		MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clear or preset to output $C_L = 15\text{pF}$ , $R_L = 400\Omega$		16	25	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clear or preset to output $C_L = 15\text{pF}$ , $R_L = 400\Omega$		25	40	ns
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output $C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	16	25	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output $C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	25	40	ns

\* For options shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

The S5473/N7473 J-K flip-flop is based on the master-slave principle. Inputs to the master section are controlled by the clock pulse. The clock pulse also regulates the state of the coupling transistors which connect the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from J and K inputs to master
3. Disable J and K inputs
4. Transfer information from master to slave.

### TRUTH TABLE

#### LOGIC

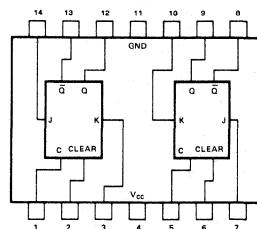
(Each Flip-Flop)		
$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

#### NOTES:

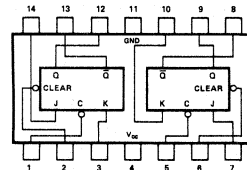
1.  $t_n$  = Bit time before clock pulse.
2.  $t_{n+1}$  = Bit time after clock pulse.

### PIN CONFIGURATIONS

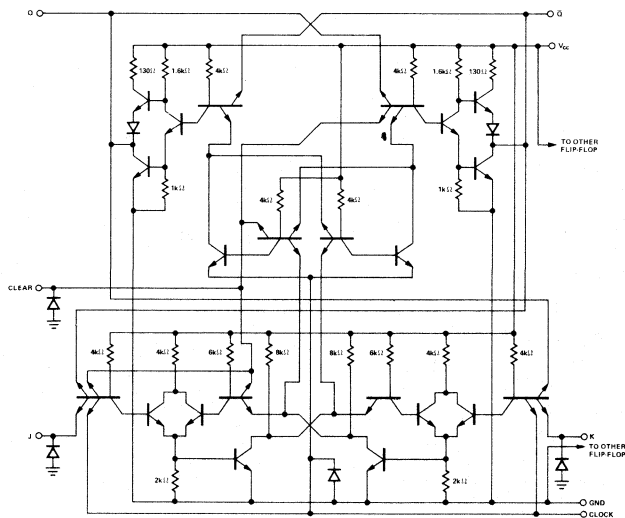
#### W PACKAGE



#### A,F PACKAGE



### SCHEMATIC (each flip-flop)



NOTE: Component values shown are nominal.

# SIGNETICS DUAL J-K MASTER-SLAVE FLIP-FLOP ■ S5473, N7473

## RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5473 Circuits	4.5	5	5.5	V
N7473 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S5473 Circuits	-55	25	125	°C
N7473 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	20			ns
Width of Clear Pulse, $t_{p(\text{clear})}$	25			ns
Input Setup Time, $t_{\text{setup}}$	$\geq t_{p(\text{Clock})}$			
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2		V	
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$ ,		0.8	V	
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ ,	2.4	3.5	V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ ,		0.22	V	
$I_{in(0)}$	Logical 0 level input current at J or K	$V_{CC} = \text{MAX}$ ,		-1.6	mA	
$I_{in(0)}$	Logical 0 level input current at clear or clock	$V_{CC} = \text{MAX}$ ,		-3.2	mA	
$I_{in(1)}$	Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4V$	40	$\mu A$	
$I_{in(1)}$	Logical 1 level input current at clear or clock	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5V$	1	mA	
$I_{in(1)}$	Logical 1 level input current at clear or clock	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4V$	80	$\mu A$	
$I_{in(1)}$	Logical 1 level input current at clear or clock	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5V$	1	mA	
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$	S5473 -20	-57	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5V$	N7473 -18	-57	mA
				20	40	mA

## SWITCHING CHARACTERISTICS, $V_{CC}=5V$ , $T_A=25^\circ C$ , N=10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$	Maximum clock frequency	$C_L = 15pF$ ,	15	20	MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clear to output	$R_L = 400\Omega$	16	25	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clear to output	$C_L = 15pF$ ,	25	40	ns
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output	$R_L = 400\Omega$	10	16	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output	$C_L = 15pF$ ,	10	25	ns
		$R_L = 400\Omega$		40	

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

The S5474/N7474 is a monolithic, dual, D-type, edge-triggered flip-flop featuring direct clear and preset inputs and complementary Q and  $\bar{Q}$  outputs. Input information is transferred to the Q output on the positive edge of the clock pulse.

Clock triggering occurs at a voltage level of the clock pulse and is not directly related to the transition time of the positive going pulse. After the clock input threshold voltage has been passed, the data input (D) is locked out.

### TRUTH TABLE

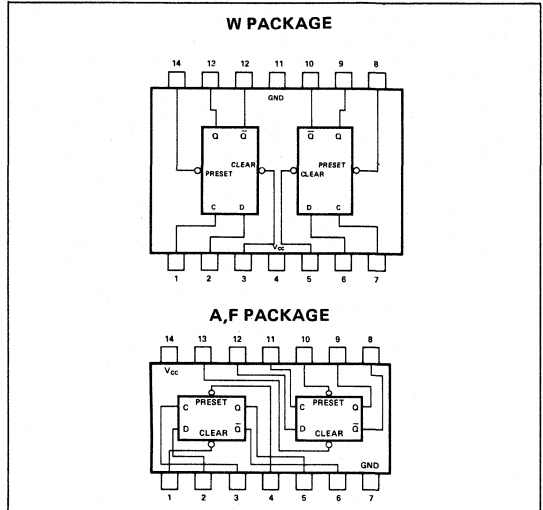
$D_n$	$Q_{n+1}$	$\bar{Q}_{n+1}$
1	1	0
0	0	1

Preset	Clear	Q
1	1	Q
1	0	0
0	1	1
0	0	†

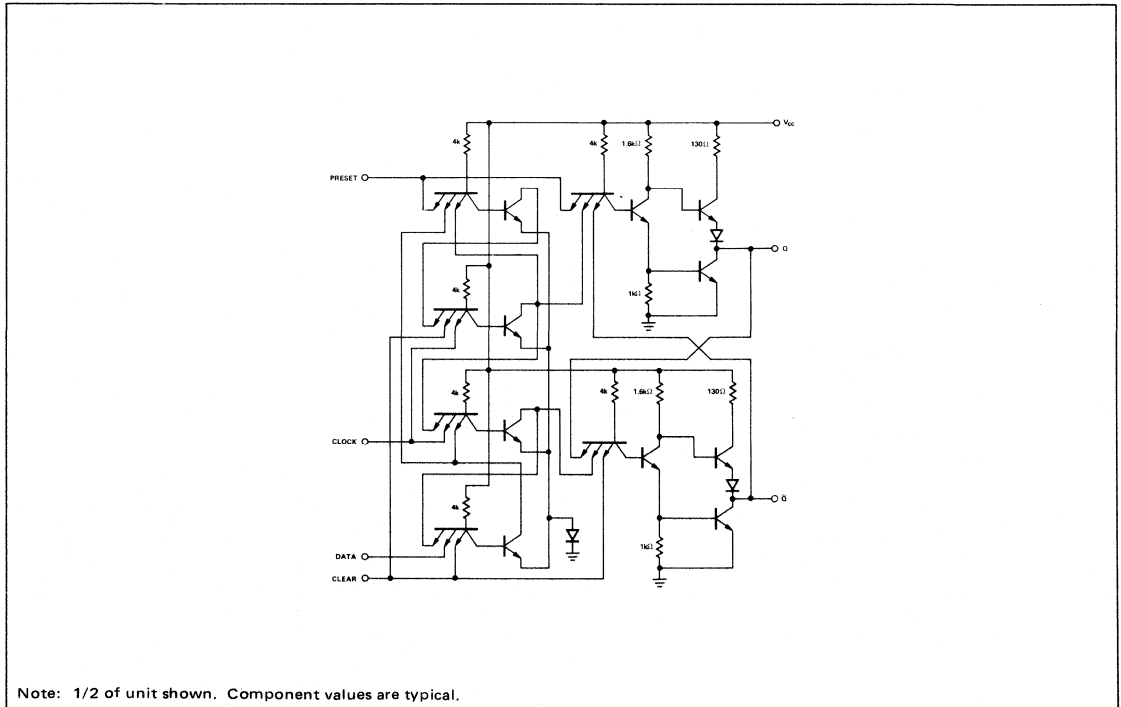
† Both outputs in 1 state  
n is time prior to clock  
n+1 is time following clock

### PIN CONFIGURATIONS



**POSITIVE LOGIC** — Low input to preset sets Q to logical 1  
Low input to clear sets Q to logical 0; Preset and clear are independent of clock

### SCHEMATIC DIAGRAM



Note: 1/2 of unit shown. Component values are typical.

# SIGNETICS DUAL D-TYPE EDGE-TRIGGERED FLIP-FLOP ■ S5474, N7474

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5474 Circuits N7474 Circuits	4.5 4.75	5 5	5.5 5.25	V V
Operating Free-Air Temperature Range, $T_A$ : S5474 Circuits N7474 Circuits	-55 0	25 25	125 70	$^{\circ}$ C $^{\circ}$ C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	30			ns
Width of Preset Pulse, $t_p(\text{preset})$	30			ns
Width of Clear Pulse, $t_p(\text{clear})$	30			ns

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	2.4	3.5		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$		0.22	0.4	V
$I_{in(0)}$ Logical 0 level input current at preset or D	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at clear or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(1)}$ Logical 1 level input current at D	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at preset or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at clear	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			120 1	$\mu\text{A}$ mA
$I_{OS}$ Short circuit output current†	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	S5474 N7474	-20 -18	-57 -57	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 5\text{V}$		17	30	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^{\circ}\text{C}$ , $N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum clock frequency	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	15	25		MHz
$t_{\text{setup}}$ Minimum input setup time	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		15	20	ns
$t_{\text{hold}}$ Minimum input hold time	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		2	5	ns
$t_{\text{pd1}}$ Propagation delay time to logical 1 level from clear or preset to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$			.25	ns
$t_{\text{pd0}}$ Propagation delay time to logical 0 level from clear or preset to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$			40	ns
$t_{\text{pd1}}$ Propagation delay time to logical 1 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	14	25	ns
$t_{\text{pd0}}$ Propagation delay time to logical 0 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	20	40	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^{\circ}\text{C}$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

The S5475B/N7475B is a monolithic, quadruple, bistable latch with complementary Q and  $\bar{Q}$  outputs. Information present at a data (D) input is transferred to the Q output when the clock is high, and the Q output will follow the data input as long as the clock remains high. When the clock goes low, the information (that was present at the data input at the time the transition occurred) is retained at the Q output until the clock is permitted to go high.

This latch is ideally suited for use as temporary storage for binary information between processing units and input/output or indicator units.

### TRUTH TABLE

#### LOGIC

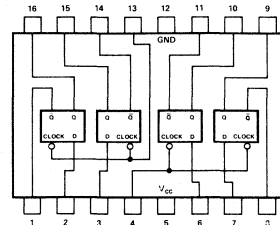
(Each Latch)		
$t_n$	$t_{n+1}$	
D	Q	$\bar{Q}$
1	1	0
0	0	1

#### NOTES:

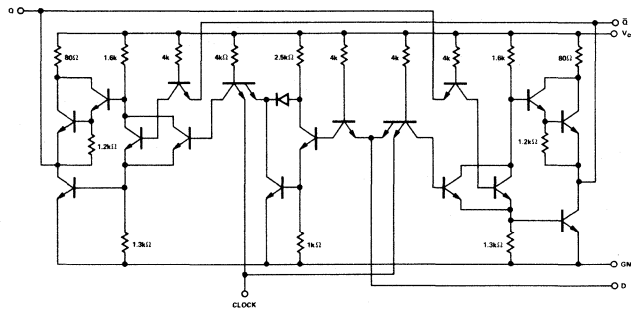
1.  $t_n$  = bit time before clock pulse.
2.  $t_{n+1}$  = bit time after clock pulse
3. These voltages are with respect to network ground terminal.

### PIN CONFIGURATIONS

#### B PACKAGE



### SCHEMATIC (each latch)



NOTE: Component values shown are nominal.

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ (See Note 3):	4.5	5	5.5	V
S5475 Circuits	4.75	5	5.25	V
N7475 Circuits			10	
Normalized Fan-Out from Outputs			10	
Operating Free-Air Temperature Range, $T_A$ :	-55	25	125	$^{\circ}C$
S5475 Circuits	0	25	70	$^{\circ}C$
N7475 Circuits				

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 level at any input terminal	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Input voltage required to ensure logical 0 level at any input terminal	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu A$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$		0.4	V



# SIGNETICS QUADRUPLE BISTABLE LATCH ■ S5475, N7475

## ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{in(0)}$	Logical 0 level input current at D	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(0)}$	Logical 0 level input current at clock	$V_{CC} = \text{MAX}$ ,				-6.4	mA
$I_{in(1)}$	Logical 1 level input current at D	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$			80	$\mu\text{A}$
		$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$			160	$\mu\text{A}$
		$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5\text{V}$			1	mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$ ,	S5475	-20		-75	mA
		$V_{out} = 0$	N7475	-18		-75	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ ,	S5475		32	46	mA
			N7475		32	53	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , $N = 10$

PARAMETER		TEST CONDITIONS NOTE A		MIN	TYP	MAX	UNIT
$t_{setup1}$	Minimum logical 1 level input setup time at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		7	20	ns
$t_{setup0}$	Minimum logical 0 level input setup time at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		14	20	ns
$t_{hold1}$	Maximum logical 1 level input hold time required at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$	0	15¶		ns
$t_{hold0}$	Maximum logical 0 level input hold time required at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$	0	6¶		ns
$t_{pd1(D-Q)}$	Propagation delay time to logical 1 level from D input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		16	30	ns
$t_{pd0(D-Q)}$	Propagation delay time to logical 0 level from D input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		14	25	ns
$t_{pd1(D-\bar{Q})}$	Propagation delay time to logical 1 level from D input to $\bar{Q}$ output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		24	40	ns
$t_{pd0(D-\bar{Q})}$	Propagation delay time to logical 0 level from D input to $\bar{Q}$ output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		7	15	ns
$t_{pd1(C-Q)}$	Propagation delay time to logical 1 level from clock input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		16	30	ns
$t_{pd0(C-Q)}$	Propagation delay time to logical 0 level from clock input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		7	15	ns
$t_{pd1(C-\bar{Q})}$	Propagation delay time to logical 1 level from clock input to $\bar{Q}$ output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		16	30	ns
$t_{pd0(C-\bar{Q})}$	Propagation delay time to logical 0 level from clock input to $\bar{Q}$ output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		7	15	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

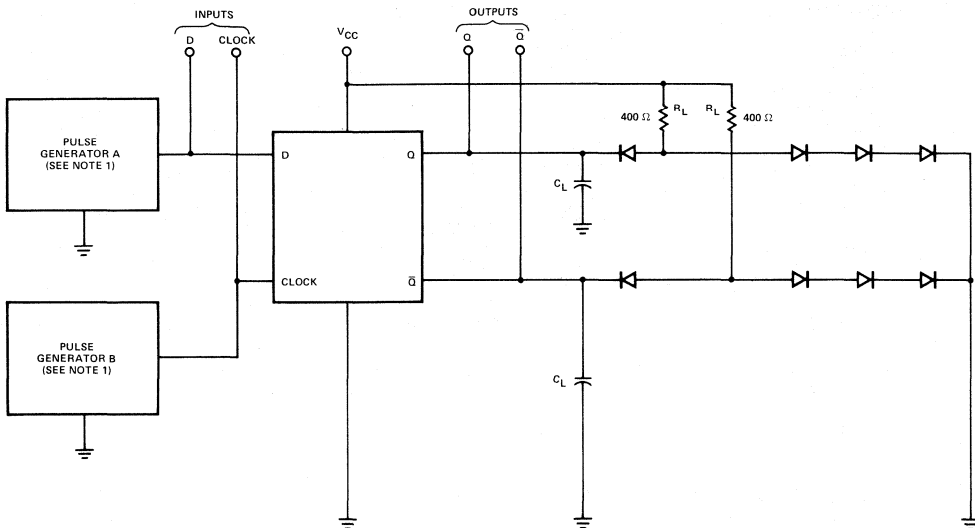
† Not more than one output should be shorted at a time.

¶ These typical times indicate that period occurring prior to the fall of clock pulse ( $t_0$ ) below 1.5V when data at the D input will still be recognized and stored.

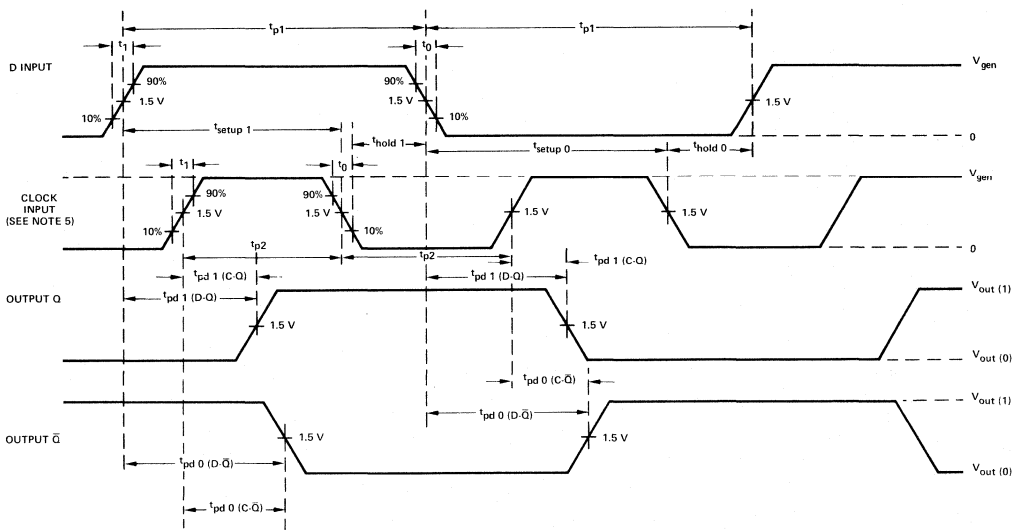
Note A AC Test circuit, voltage waveforms and switching times are given on page 2-76.

SWITCHING CHARACTERISTICS\*

TEST CIRCUIT



VOLTAGE WAVEFORMS AND SWITCHING TIMES



- NOTES: 1. The pulse generators have the following characteristics:  $V_{gen} = 3\text{ V}$ ,  $t_1 = t_2 \leq 10\text{ ns}$ , and  $Z_{out} \approx 50\ \Omega$ . For pulse generator A  $t_{p1} = 1\ \mu\text{s}$  and  $PRR = 500\text{ kHz}$ . For pulse generator B,  $t_{p2} = 500\text{ ns}$  and  $PRR = 1\text{ MHz}$ . Positions of D-input and clock-input pulses are varied with respect to each other to verify setup and hold times.
2. Each latch is tested separately.
3.  $C_L$  includes probe and jig capacitance.
4. All diodes are 1N3064.
5. When measuring  $t_{pd1}(D-Q)$  and  $t_{pd0}(D-Q)$  (or  $t_{pd0}(D-\bar{Q})$  and  $t_{pd1}(D-\bar{Q})$  for the S5474/N7475), clock input must be held at logical 1.

\*Complementary Q outputs are on the S5475/N7475 only.

### DESCRIPTION

The S5476B/N7476B J-K flip-flop is based on the master-slave principle. Inputs to the master section are controlled by the clock pulse. The clock pulse also regulates the state of the coupling transistors which connect the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from J and K inputs to master
3. Disable J and K inputs
4. Transfer information from master to slave.

### TRUTH TABLE

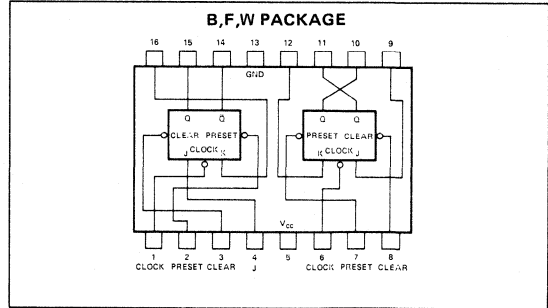
#### LOGIC

(Each Flip-Flop)		
$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

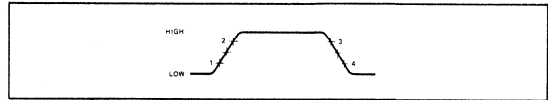
#### NOTES:

1.  $t_n$  = bit time before clock pulse.
2.  $t_{n+1}$  = bit time after clock pulse.

### PIN CONFIGURATIONS



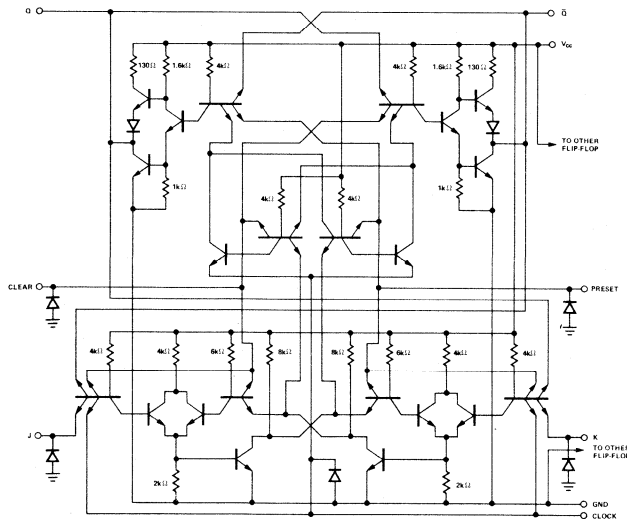
### CLOCK WAVEFORM



### POSITIVE LOGIC

- Low input to preset sets Q to logical 1
- Low input to clear sets Q to logical 0
- Clear and preset are independent from clock

### SCHEMATIC (each flip-flop)



NOTE: Component values shown are nominal.

# SIGNETICS DUAL J-K MASTER-SLAVE FLIP-FLOP WITH PRESET AND CLEAR ■ S5476, N7476

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5476 Circuits	4.5	5	5.5	V
N7476 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S5476 Circuits	-55	25	125	°C
N7476 Circuits	0	25	70	°C
Normalized Fanout from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	20			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	25			ns
Width of Clear Pulse, $t_{p(\text{clear})}$	25			ns
Input Setup Time, $t_{\text{setup}}$	$\geq t_{p(\text{clock})}$			
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -400\mu\text{A}$	2.4	3.5		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 16\text{mA}$		0.22	0.4	V
$I_{in(0)}$ Logical 0 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at clear, preset, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(1)}$ Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at clear, preset, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA
$I_{OS}$ Short circuit output current†	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	S5476	-20	-57	mA
$I_{CC}$ Supply current (each flip-flop)	$V_{CC} = \text{MAX}$ , $V_{in} = 5\text{V}$		20	40	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum clock frequency	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	15	20		MHz
$t_{pd1}$ Propagation delay time to logical 0 level from clear or preset to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		16	25	ns
$t_{pd0}$ Propagation delay time to logical 1 level from clear or preset to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		25	40	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	16	25	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	25	40	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

S5477W

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The S5477Q/N7477Q is a monolithic, quadruple, bistable latch with Q outputs. Information present at a data (D) input is transferred to the Q output when the clock is high, and the Q output will follow the data input as long as the clock remains high. When the clock goes low, the information (that was present at the data input at the time the transition occurred) is retained at the Q output until the clock is permitted to go high.

This latch is ideally suited for use as temporary storage for binary information between processing units and input/output or indicator units.

### TRUTH TABLE

#### LOGIC

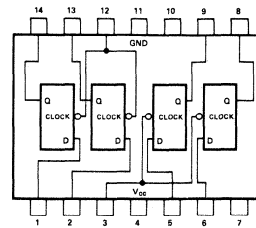
(Each Latch)	
$t_n$	$t_{n+1}$
D	Q
1	1
0	0

#### NOTES:

1.  $t_n$  = bit time before clock pulse.
2.  $t_{n+1}$  = bit time after clock pulse.
3. These voltages are with respect to network ground terminal.

### PIN CONFIGURATIONS

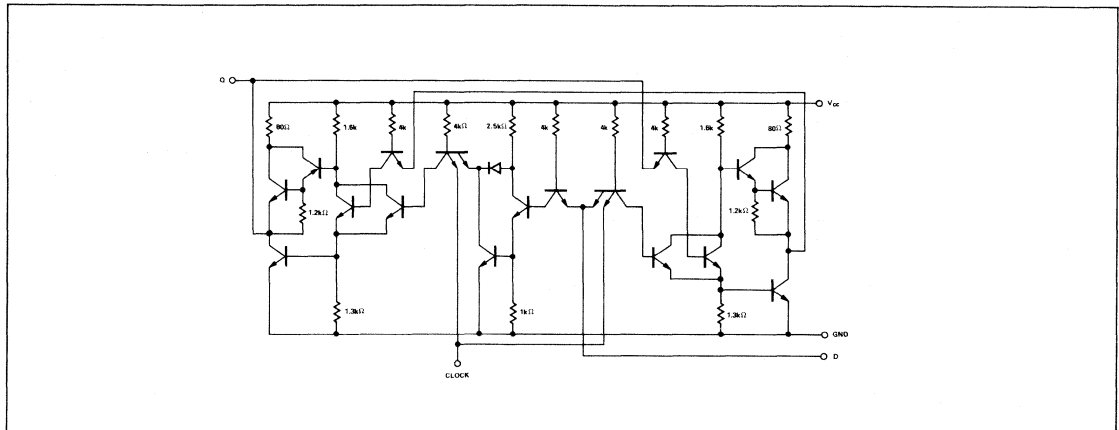
#### W PACKAGE



### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ (See Note 3): S5477 Circuits N7477 Circuits	4.5	5	5.5	V
	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S5477 Circuits	-55	25	125	$^{\circ}C$

### SCHEMATIC (each latch)



# SIGNETICS QUADRUPLE BISTABLE LATCH ■ S5477

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 level at any input terminal	$V_{CC} = \text{MIN}$		2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 level at any input terminal	$V_{CC} = \text{MIN}$				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ ,	$I_{load} = -400\mu\text{A}$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ ,	$I_{sink} = 16\text{mA}$			0.4	V
$I_{in(0)}$	Logical 0 level input current at D	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(0)}$	Logical 0 level input current at clock	$V_{CC} = \text{MAX}$ ,				-6.4	mA
$I_{in(1)}$	Logical 1 level input current at D	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$			80	$\mu\text{A}$
		$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$			160	$\mu\text{A}$
		$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5\text{V}$			1	mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$ ,	S5477	-20		-75	mA
		$V_{out} = 0$					
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ ,	S5477		32	46	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ ,  $N = 10$

PARAMETER		TEST CONDITIONS NOTE A		MIN	TYP	MAX	UNIT
$t_{setup1}$	Minimum logical 1 level input setup time at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		7	20	ns
$t_{setup0}$	Minimum logical 0 level input setup time at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		14	20	ns
$t_{hold1}$	Maximum logical 1 level input hold time required at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$	0	15¶		ns
$t_{hold0}$	Maximum logical 0 level input hold time required at D input	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$	0	6¶		ns
$t_{pd1(D-Q)}$	Propagation delay time to logical 1 level from D input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		16	30	ns
$t_{pd0(D-Q)}$	Propagation delay time to logical 0 level from D input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		14	25	ns
$t_{pd1(C-Q)}$	Propagation delay time to logical 1 level from clock input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		16	30	ns
$t_{pd0(C-Q)}$	Propagation delay time to logical 0 level from clock input to Q output	$C_L = 15\text{pF}$ ,	$R_L = 400\Omega$		7	15	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

¶ These typical times indicate that period occurring prior to the fall of clock pulse ( $t_0$ ) below 1.5V when data at the D input will still be recognized and stored.

NOTE A: AC Test circuit, voltage waveforms and switching times are given on page 2-76

#### DESCRIPTION

The S5480/N7480 is a single-bit, high-speed, binary full adder with gated complementary inputs, complementary sum ( $\Sigma$  and  $\bar{\Sigma}$ ) outputs and inverted carry output. Designed for medium- and high-speed, multiple-bit, parallel-add/serial-carry applications, the circuit (see schematic diagram) utilizes diode-transistor logic (DTL) for the gated inputs, and high-speed, high-fan-out transistor-transistor logic (TTL) for the sum and carry outputs. The circuit is entirely compatible with both DTL and TTL logic families. The implementation of a single-inversion, high-speed, Darlington-connected serial-carry circuit minimizes the necessity for extensive "look-ahead" and carry-cascading circuits. The power dissipation has been maintained considerably below that attainable with equivalent standard integrated circuits connected to perform full-adder functions.

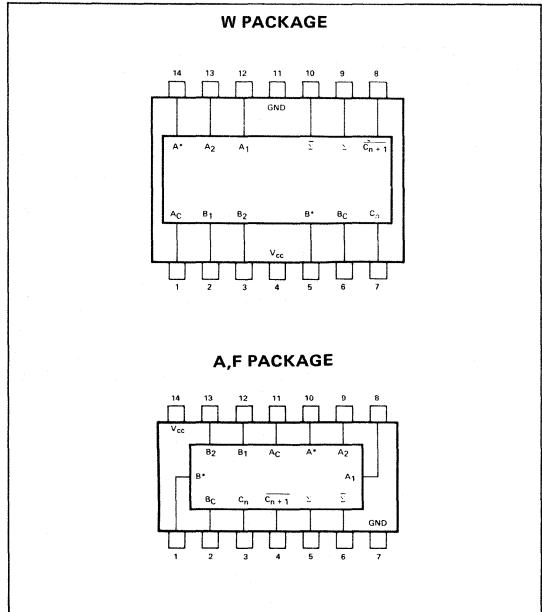
#### TRUTH TABLE (See Notes 1, 2, and 3)

LOGIC						
$C_n$	B	A	$C_{n+1}$	$\bar{\Sigma}$	$\Sigma$	
0	0	0	1	1	0	
0	0	1	1	0	1	
0	1	0	1	0	1	
0	1	1	0	1	0	
1	0	0	1	0	1	
1	0	1	0	1	0	
1	1	0	0	1	0	
1	1	1	0	0	1	

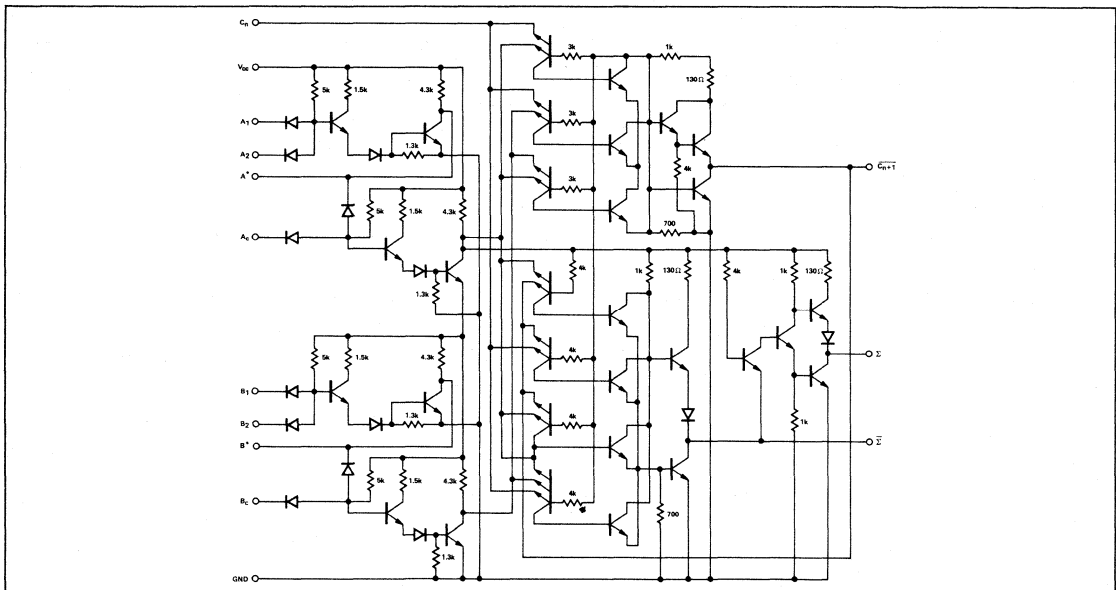
#### NOTES:

- $A = A^* \cdot \bar{A}_C$ ,  $B = B^* \cdot \bar{B}_C$  where  $A^* = \bar{A}_1 \cdot \bar{A}_2$ ,  $B^* = \bar{B}_1 \cdot \bar{B}_2$ .
- When  $A^*$  or  $B^*$  are used as inputs,  $A_1$  and  $A_2$  or  $B_1$  and  $B_2$  respectively, must be connected to GND.

#### PIN CONFIGURATIONS



#### SCHEMATIC DIAGRAM



# SIGNETICS GATED FULL ADDER ■ S5480, N7480

## RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5480 Circuits	4.5	5	5.25	V
N7480 Circuits	4.75	5	5.25	V
Normalized Fan-Out from Outputs: $C_{n+1}$ , N			5	
$\Sigma$ or $\bar{\Sigma}$ , N			10	
A* or B*, N			3	
Operating Free-Air Temperature Range, $T_A$ : S5480 Circuits	-55	25	125	°C
N7480 Circuits	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage	$V_{CC} = \text{MIN}$		2			V
$V_{in(0)}$	Logical 0 input voltage	$V_{CC} = \text{MIN}$				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$		2.4	3.5		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$			0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current at $A_1$ , $A_2$ , $B_1$ , $B_2$ , $A_C$ or $B_C$	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4V$			-1.6	mA
$I_{in(0)}$	Logical 0 level input current at A* or B*	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4V$			-2.6	mA
$I_{in(0)}$	Logical 0 level input current at $C_n$	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4V$			-8	mA
$I_{in(1)}$	Logical 1 level input current at $A_1$ , $A_2$ , $B_1$ , $B_2$ , $A_C$ or $B_C$	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4V$			15	$\mu A$
		$V_{CC} = \text{MAX}$	$V_{in} = 5.5V$			1	mA
$I_{in(1)}$	Logical 1 level input current at $C_n$	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4V$			200	$\mu A$
		$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5V$			1	mA
$I_{OS}$	Short circuit output current at $\Sigma$ or $\bar{\Sigma}$ †	$V_{CC} = \text{MAX}$ ,		S5480	-20	-57	mA
				N7480	-18	-57	mA
$I_{OS}$	Short circuit output current at $C_{n+1}$ †	$V_{CC} = \text{MAX}$ ,		S5480	-20	-70	mA
				N7480	-18	-70	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ ,		S5480	21	31	mA
				N7480	21	35	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^\circ C$

PARAMETER††	FROM INPUT	TO OUTPUT	TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd1}$	$C_n$	$C_{n+1}$	$C_L = 15pF$ ,	$R_L = 780\Omega$		13	17	ns
$t_{pd0}$			$C_L = 15pF$ ,	$R_L = 780\Omega$		8	12	ns
$t_{pd1}$	$B_C$	$C_{n+1}$	$C_L = 15pF$ ,	$R_L = 780\Omega$		18	25	ns
$t_{pd0}$			$C_L = 15pF$ ,	$R_L = 780\Omega$		38	55	ns
$t_{pd1}$	$A_C$	$\Sigma$	$C_L = 15pF$ ,	$R_L = 400\Omega$		52	70	ns
$t_{pd0}$			$C_L = 15pF$ ,	$R_L = 400\Omega$		62	80	ns
$t_{pd1}$	$B_C$	$\bar{\Sigma}$	$C_L = 15pF$ ,	$R_L = 400\Omega$		38	55	ns
$t_{pd0}$			$C_L = 15pF$ ,	$R_L = 400\Omega$		56	75	ns
$t_{pd1}$	$A_1$	$A^*$	$C_L = 15pF$			48	65	ns
$t_{pd0}$			$C_L = 15pF$			17	25	ns
$t_{pd1}$	$B_1$	$B^*$	$C_L = 15pF$			48	65	ns
$t_{pd0}$			$C_L = 15pF$			17	25	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

† Not more than one output should be shorted at a time.

††  $t_{pd1}$  is propagation delay time to logical 1 level.  $t_{pd0}$  is propagation delay time to logical 0 level.



### DESCRIPTION

The 54/7483 is a 4-Bit Binary Full Adder for adding two four bit binary numbers. A Carry Look Ahead circuit is included to provide minimum carry propagation delays.

Propagation delays of carry-in to carry-out is typically 12 nsec.

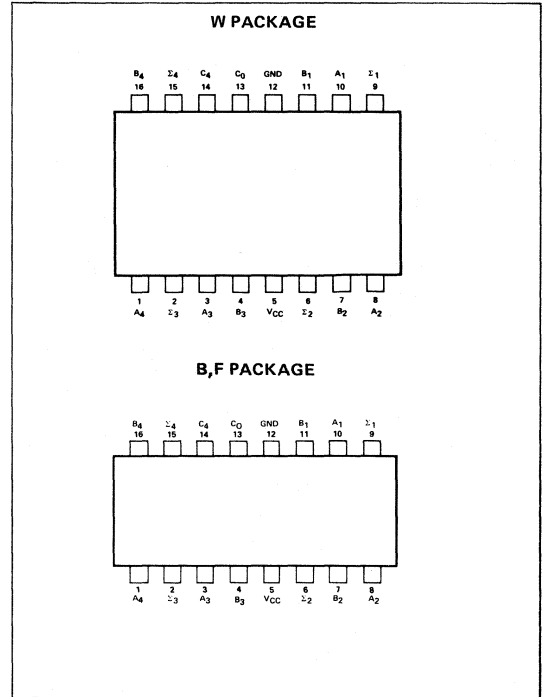
### TRUTH TABLE

INPUT				OUTPUT								
				WHEN $C_0 = 0$				WHEN $C_0 = 1$				
				WHEN $C_2 = 0$				WHEN $C_2 = 1$				
$A_1/B_1$	$A_2/B_2$	$A_3/B_3$	$A_4/B_4$	$\Sigma_1$	$\Sigma_2$	$C_2$	$\Sigma_1$	$\Sigma_2$	$C_2$	$\Sigma_3$	$\Sigma_4$	$C_4$
$A_3$	$B_3$	$A_4$	$B_4$	$\Sigma_3$	$\Sigma_4$	$C_4$	$\Sigma_3$	$\Sigma_4$	$C_4$	$\Sigma_3$	$\Sigma_4$	$C_4$
0	0	0	0	0	0	0	1	0	0	0	0	0
1	0	0	0	1	0	0	0	1	0	0	0	0
0	1	0	0	1	0	0	0	0	1	0	0	0
1	1	0	0	0	1	0	1	1	0	0	0	0
0	0	1	0	0	1	0	1	1	1	0	0	0
1	0	1	0	1	1	0	0	0	0	0	1	0
0	1	1	0	1	1	0	0	0	0	0	1	0
1	1	1	0	0	0	1	1	1	0	0	1	0
0	0	0	1	0	1	0	1	1	1	0	0	1
1	0	0	1	1	1	0	0	0	0	0	1	0
0	1	0	1	1	1	0	0	0	0	0	1	0
1	1	0	1	0	0	1	1	1	0	0	1	0
0	0	1	1	0	0	1	1	1	0	0	1	0
1	0	1	1	1	1	0	0	1	1	0	1	0
0	0	1	1	0	0	1	1	1	0	1	0	1
1	0	1	1	1	1	0	0	1	1	0	1	1
0	1	1	1	1	1	0	1	0	1	1	1	1
1	1	1	1	0	1	1	1	1	1	1	1	1

### NOTES:

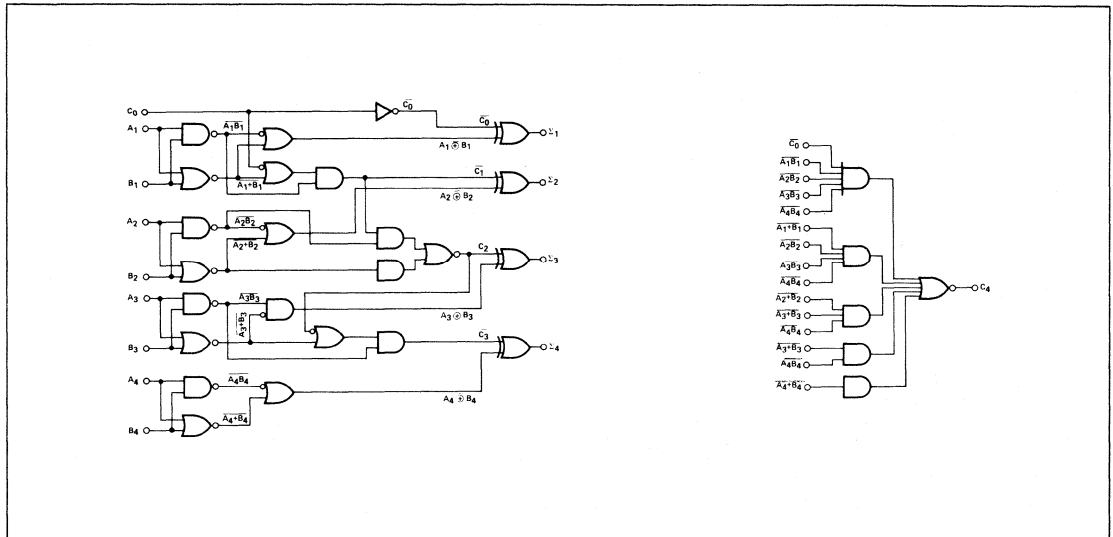
Input conditions at  $A_1$ ,  $A_2$ ,  $B_1$ ,  $B_2$ , and  $C_0$  are used to determine outputs  $\Sigma_1$  and  $\Sigma_2$ , and the value of the internal carry  $C_2$ . The

### PIN CONFIGURATIONS



values at  $C_2$ ,  $A_3$ ,  $B_3$ ,  $A_4$ , and  $B_4$ , are then used to determine outputs  $\Sigma_3$ ,  $\Sigma_4$ , and  $C_4$ .

### LOGIC DIAGRAM



# SIGNETICS 4-BIT BINARY FULL ADDER (LOOK AHEAD CARRY) ■ S5483, N7483

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : (See Note 1)	S5483 Circuits	4.5	5	5.5	V
	N7483 Circuits	4.75	5	5.25	V
Normalized Fan-Out From Outputs: $C_4$ $\Sigma_1, \Sigma_2, \Sigma_3$ or $\Sigma_4$				5	
				10	

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$			0.4	V
$I_{in(0)}$ Logical 0 level input current at $A_1, A_3, B_1, B_3,$ or $C_0$	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			-3.2	mA
$I_{in(0)}$ Logical 0 level input current at $A_2, A_4, B_2,$ or $B_4$	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			-1.6	mA
$I_{in(1)}$ Logical 1 level input current at $A_1, A_3, B_1, B_3,$ or $C_0$	$V_{CC} = \text{MAX}, V_{in} = 2.4V$			80	$\mu A$
	$V_{CC} = \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{in(1)}$ Logical 1 level input current at $A_2, A_4, B_2,$ or $B_4$	$V_{CC} = \text{MAX}, V_{in} = 2.4V$			40	$\mu A$
	$V_{CC} @ \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{OS}$ Short-circuit output current at $\Sigma_1, \Sigma_2, \Sigma_3,$ or $\Sigma_4$ †	$V_{CC} = \text{MAX}$ S5483	-20		-55	mA
	$V_{CC} = \text{MAX}$ N7483	-18		-55	mA
$I_{OS}$ Short-circuit output current at $C_4$ †	$V_{CC} = \text{MAX}$ S5483	-20		-70	mA
	$V_{CC} = \text{MAX}$ N7483	-18		-70	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$		58	79	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C,$ unless otherwise noted $N = 10$

PARAMETER ‡	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd1}$ From $C_0$ to 1	$C_L = 50pF, R_L = 400\Omega$		23	34	ns
$t_{pd0}$ From $C_0$ to 1	$C_L = 50pF, R_L = 400\Omega$		20	34	ns
$t_{pd1}$ From $C_0$ to 2	$C_L = 50pF, R_L = 400\Omega$		24	35	ns
$t_{pd0}$ From $C_0$ to 2	$C_L = 50pF, R_L = 400\Omega$		22	35	ns
$t_{pd1}$ From $C_0$ to 3	$C_L = 50pF, R_L = 400\Omega$		30	50	ns
$t_{pd0}$ From $C_0$ to 3	$C_L = 50pF, R_L = 400\Omega$		24	40	ns
$t_{pd1}$ From $C_0$ to 4	$C_L = 50pF, R_L = 400\Omega$		30	50	ns
$t_{pd0}$ From $C_0$ to 4	$C_L = 50pF, R_L = 400\Omega$		28	50	ns
$t_{pd1}$ From $C_0$ to $C_4$	$C_L = 50pF, R_L = 780\Omega$		12	20	ns
$t_{pd0}$ From $C_0$ to $C_4$	$C_L = 50pF, R_L = 780\Omega$		12	20	ns
$t_{pd1}$ From $A_2$ or $B_2$ to 2	$C_L = 50pF, R_L = 400\Omega$			40	ns
$t_{pd0}$ From $A_2$ or $B_2$ to 2	$C_L = 50pF, R_L = 400\Omega$			35	ns
$t_{pd1}$ From $A_4$ of $B_4$ to 4	$C_L = 50pF, R_L = 400\Omega$			40	ns
$t_{pd0}$ From $A_4$ of $B_4$ to 4	$C_L = 50pF, R_L = 400\Omega$			35	ns

†  $T_{pd1}$  is propagation delay time to logical 1 level.  $t_{pd0}$  is propagation delay time to logical 0 level.

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C.$

† Not more than one output should be shorted at a time.

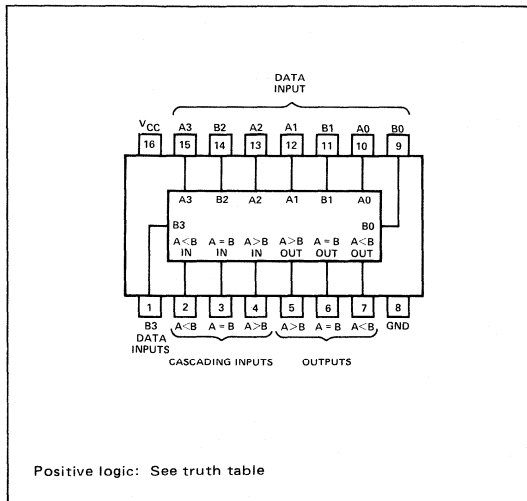
NOTE 1: These voltage values are with respect to network ground terminal.

### DESCRIPTION

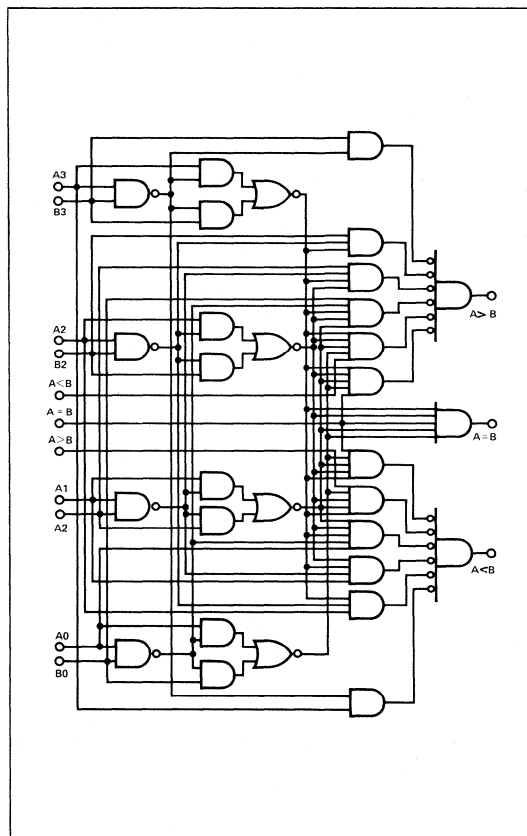
The S5485 and N7485 perform magnitude comparison of straight binary and straight BCD (8421) codes. Three fully decoded decisions about two 4-bit words (A, B) are made and are externally available at three outputs. These devices are fully expandable to any number of bits without external gates. When cascaded, the total time for comparison is the function of the word length; however, only a two-gate-level delay (12 ns) is added for each four-bit expansion.

These circuits are completely compatible with most TTL and DTL families. Typical average power dissipation is 275 milliwatts. The S5485 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; The N7485 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### PIN CONFIGURATION



### FUNCTIONAL BLOCK DIAGRAM



### TRUTH TABLE

COMPARING INPUTS				CASCADING INPUTS			OUTPUTS		
A3, B3	A2, B2	A1, B1	A0, B0	A > B	A < B	A = B	A > B	A < B	A = B
A3 > B3	X	X	X	X	X	X	H	L	L
A3 < B3	X	X	X	X	X	X	L	H	L
A3 = B3	A2 > B2	X	X	X	X	X	H	L	L
A3 = B3	A2 < B2	X	X	X	X	X	L	H	L
A3 = B3	A2 = B2	A1 > B1	X	X	X	X	H	L	L
A3 = B3	A2 = B2	A1 < B1	X	X	X	X	L	H	L
A3 = B3	A2 = B2	A1 = B1	A0 > B0	X	X	X	H	L	L
A3 = B3	A2 = B2	A1 = B1	A0 < B0	X	X	X	L	H	L
A3 = B3	A2 = B2	A1 = B1	A0 = B0	H	L	L	H	L	L
A3 = B3	A2 = B2	A1 = B1	A0 = B0	L	H	L	L	H	L
A3 = B3	A2 = B2	A1 = B1	A0 = B0	L	L	H	L	L	H

NOTE: H = High level, L = Low level, X = Irrelevant.

# SIGNETICS 4-BIT MAGNITUDE COMPARATORS ■ S5485, N7485

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S5485			N7485			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N			10			10	
Operating free-air temperature, $T_A$	-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$			-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -400 \mu\text{A}$	2.4			V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$			0.4	V
$I_I$	Input current at maximum	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1	mA
$I_{IH}$	High-level input current	A < B, A > B inputs	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$		40	$\mu\text{A}$
		all other inputs			120	
$I_{IL}$	Low-level input current	A < B, A > B inputs	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$		-1.6	mA
		all other inputs			-4.8	
$I_{OS}$	Short-circuit output current ‡	$V_{CC} = \text{MAX}, V_O = 0$	S5485	-20	-55	mA
			N7485	-18	-55	
$I_{CC}$	Supply current	$V_{CC} = \text{MAX},$ See Note 1		55	88	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

‡Not more than one output should be shorted at a time.

NOTE 1:  $I_{CC}$  is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

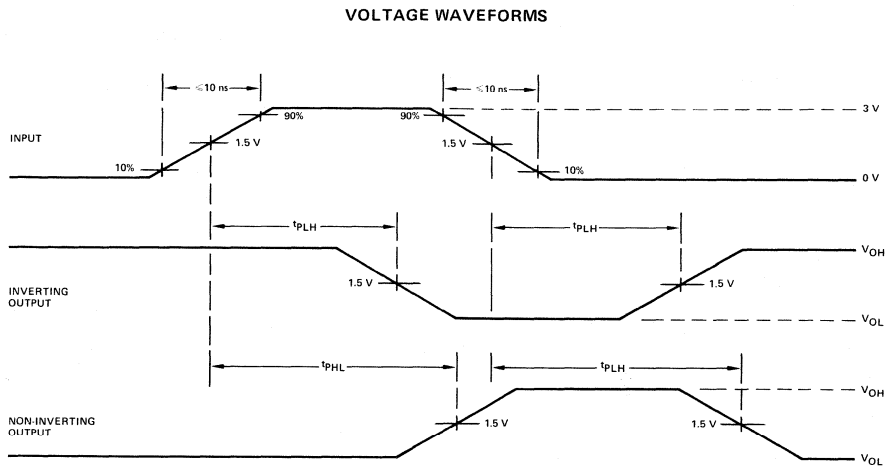
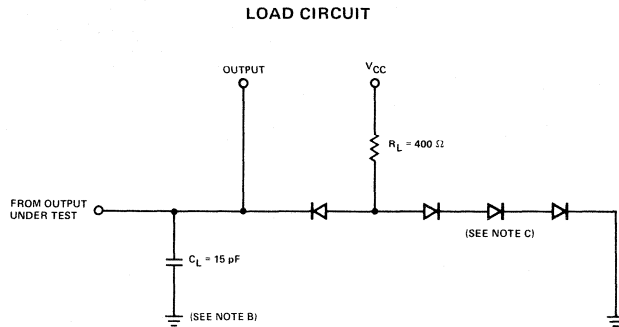
## SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	FROM INPUT	TO OUTPUT	NUMBER OF GATE LEVELS	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Any A or B data input	A > B, A < B	1	$C_L = 15 \text{ pF}, R_L = 400 \Omega,$ See Figure 1		7		ns
			2			12		
		3			17	26		
		4			23	35		
$t_{PHL}$	Any A or B data input	A < B, A > B	1			11		ns
			2			15		
		3			20	30		
		A = B	4			20	30	
$t_{PLH}$	A < B or A = B	A > B	1			7	11	ns
$t_{PHL}$	A < B or A = B	A > B	1			11	17	ns
$t_{PLH}$	A = B	A = B	2		13	20	ns	
$t_{PHL}$	A = B	A = B	2		11	17	ns	
$t_{PLH}$	A > B or A = B	A < B	1		7	11	ns	
$t_{PHL}$	A > B or A = B	A < B	1		11	17	ns	

$t_{PLH}$  ≡ Propagation delay time, low-to-high-level output.

$t_{PHL}$  ≡ Propagation delay time, high-to-low-level output.

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. Input pulses are supplied by a pulse generator having the following characteristics:  
 PRR = 1 MHz, duty cycle = 50%,  $Z_{Out} \approx 50 \Omega$ .  
 B.  $C_L$  includes probe and jig capacitance  
 C. All diodes are 1N3064

FIGURE 1. PROPAGATION DELAY TIMES

S5486-A,F,W • N7486-A,F

DIGITAL 54/74 TTL SERIES

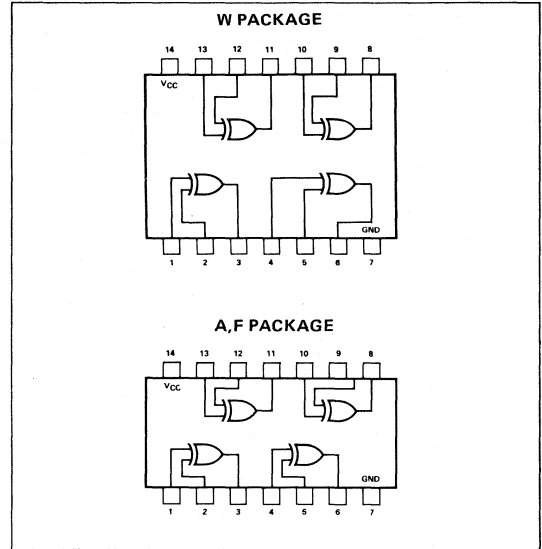
### DESCRIPTION

The 54/7486 Quad 2-Input Exclusive OR Gate is a TTL element providing the function  $\overline{A}B + A\overline{B}$  at the output.

### TRUTH TABLE

INPUTS		OUTPUT
A	B	Y
0	0	0
0	1	1
1	0	1
1	1	0

### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

PARAMETER		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$	S5486 Circuits	4.5	5	5.5	V
	N7486 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each output, N:	Logical 0			10	
	Logical 1			20	

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal $V_{CC} = \text{MIN}$		2		V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal $V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V, I_{load} = -800 \mu A$		2.4		V
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V, I_{sink} = 16mA$			0.4	V
$I_{in(1)}$	Logical 1 level input current (each input) $V_{CC} = \text{MAX}, V_{in} = 2.4V$			40	$\mu A$
$I_{in(0)}$	Logical 0 level input current (each input) $V_{CC} = \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{in(0)}$	Logical 0 level input current (each input) $V_{CC} = \text{MAX}, V_{in} = 0.4V$			-1.6	mA
$I_{OS}$	Short circuit output current† $V_{CC} = \text{MAX}, V_{in(1)} = 4.5V, V_{in(0)} = 0$			-20	mA
$I_{CC}$	Supply current $V_{CC} = \text{MAX}, V_{in} = 4.5V$	S5486		-18	mA
		N7486			
$I_{CC}$	Supply current $V_{CC} = \text{MAX}, V_{in} = 4.5V$	S5486	30	43	mA
		N7486	30	50	mA

**SIGNETICS QUAD 2-INPUT EXCLUSIVE OR GATE ■ S5486, N7486**

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level (other input low)	$C_L = 15pF$ ,	$R_L = 400$		11	17	ns
$t_{pd1}$	Propagation delay time to logical 1 level (other input low)	$C_L = 15pF$ ,	$R_L = 400$		15	23	ns
$t_{pd0}$	Propagation delay time to logical 0 level (Other input high)	$C_L = 15pF$ ,	$R_L = 400$		13	22	ns
$t_{pd1}$	Propagation delay time to logical 1 level (other input high)	$C_L = 15pF$ ,	$R_L = 400$		18	30	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

+ Not more than one output should be shorted at a time.

N7448-B,W

DIGITAL 54/74 TTL SERIES

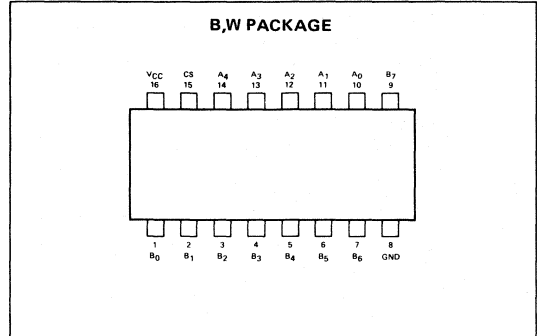
### DESCRIPTION

The 7488 is a TTL 256-Bit Read Only Memory organized as 32 word with 8 bits per word. The words are selected by five binary address lines with full word decoding incorporated on the chip. A Chip Select input is provided for additional decoding flexibility, which will cause all eight outputs to go to the high state when the Chip Select input is taken high.

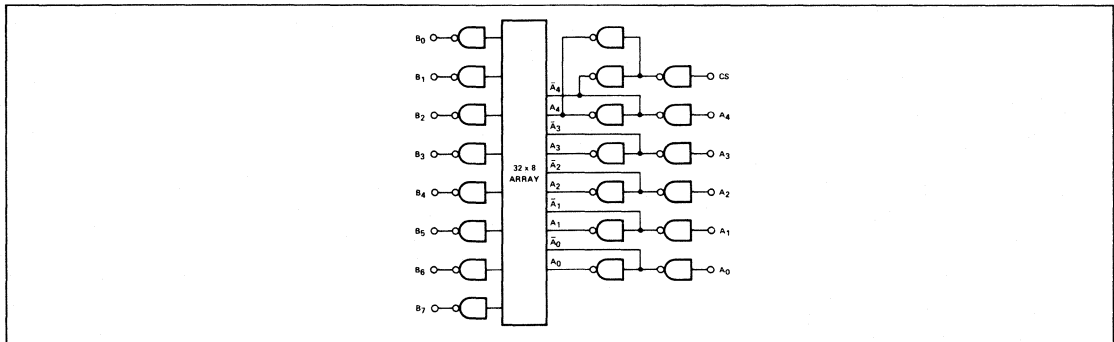
This device is fully TTL or DTL compatible. The outputs are uncommitted collectors, which allows wired-OR operation with the outputs of other TTL or DTL devices. These outputs are capable of sinking twelve standard DCL loads. Propagation delay time is 50ns maximum. Power dissipation is 310 milliwatts with 400 milliwatts maximum.

Customer may specify patterns for the 256-Bit Read Only Memory by completing the truth table/order blank.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



### ELECTRICAL CHARACTERISTICS

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<p><b>See 8223 or 8224 Data Sheet for Pin-for-Pin Replacement</b></p>					



**SIGNETICS 256-BIT READ-ONLY MEMORY ■ N7488**

256-BIT READ ONLY MEMORIES TRUTH TABLE/ORDER BLANK

CUSTOMER: _____							THIS PORTION TO BE COMPLETED BY SIGNETICS							
P.O. NO.: _____							PART NO.: _____							
YOUR PART NO.: _____							S.D. NO.: _____							
DATE: _____							DATE RECEIVED: _____							
INPUTS							OUTPUTS							
WORD	A <sub>4</sub>	A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	ENABLE	B <sub>7</sub>	B <sub>6</sub>	B <sub>5</sub>	B <sub>4</sub>	B <sub>3</sub>	B <sub>2</sub>	B <sub>1</sub>	B <sub>0</sub>
0	0	0	0	0	0	0								
1	0	0	0	0	1	0								
2	0	0	0	1	0	0								
3	0	0	0	1	1	0								
4	0	0	1	0	0	0								
5	0	0	1	0	1	0								
6	0	0	1	1	0	0								
7	0	0	1	1	1	0								
8	0	1	0	0	0	0								
9	0	1	0	0	1	0								
10	0	1	0	1	0	0								
11	0	1	0	1	1	0								
12	0	1	1	0	0	0								
13	0	1	1	0	1	0								
14	0	1	1	1	0	0								
15	0	1	1	1	1	0								
16	1	0	0	0	0	0								
17	1	0	0	0	1	0								
18	1	0	0	1	0	0								
19	1	0	0	1	1	0								
20	1	0	1	0	0	0								
21	1	0	1	0	1	0								
22	1	0	1	1	0	0								
23	1	0	1	1	1	0								
24	1	1	0	0	0	0								
25	1	1	0	0	1	0								
26	1	1	0	1	0	0								
27	1	1	0	1	1	0								
28	1	1	1	0	0	0								
29	1	1	1	0	1	0								
30	1	1	1	1	0	0								
31	1	1	1	1	1	0								
ALL	X	X	X	X	X	1	1	1	1	1	1	1	1	1

N7489-B

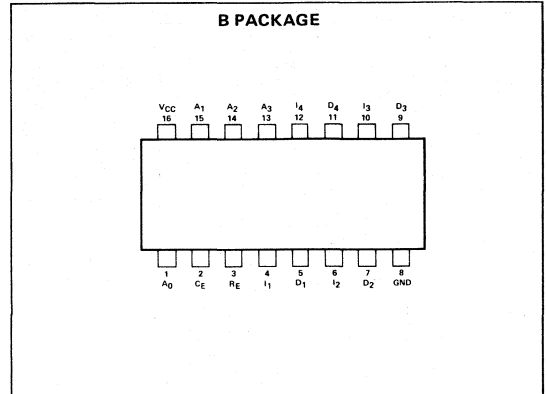
DIGITAL 54/74 TTL SERIES

### DESCRIPTION

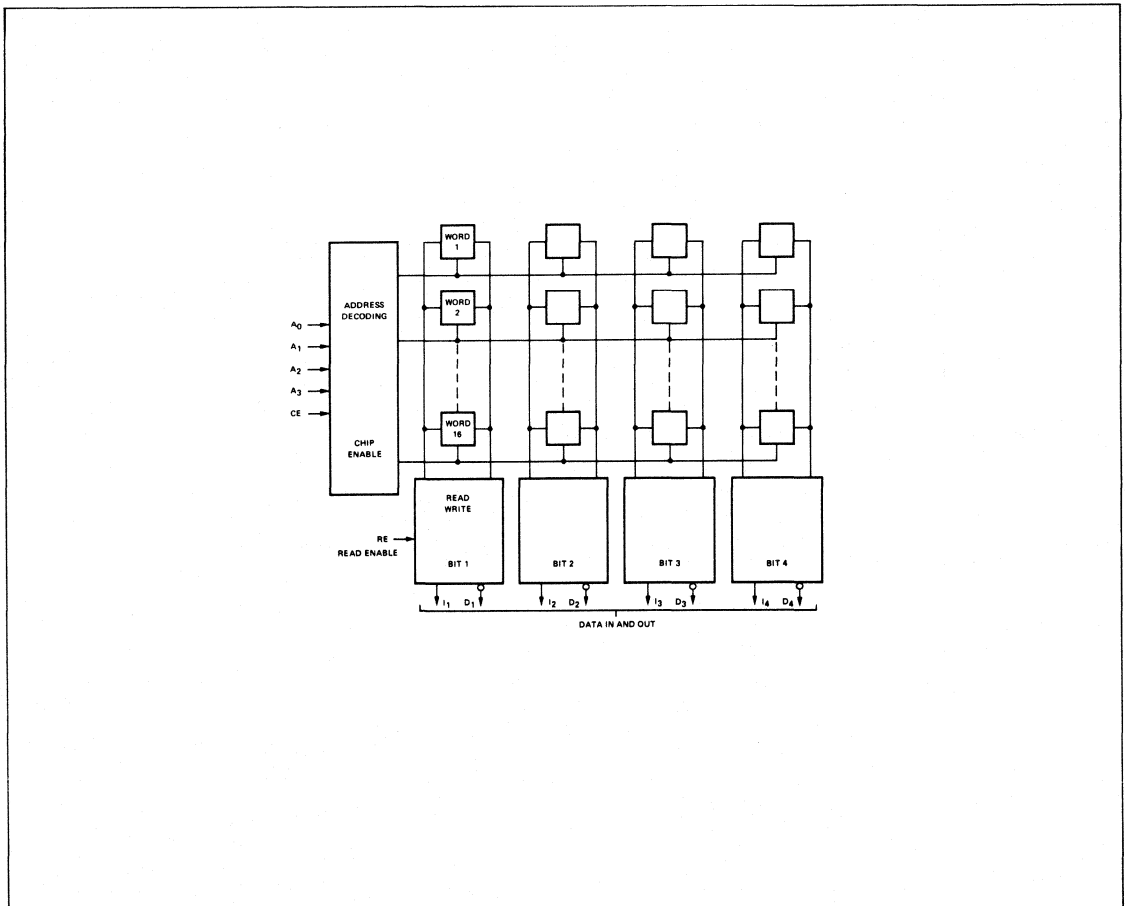
The 7489 is a TTL 64-Bit Read-Write Random Access Memory organized as 16-words of 4 bits each. The 7489 is ideally suited for application in scratch pads and high speed buffer memories.

Words are selected through a 4-input binary decoder when the chip select input (CE) is at logic "0". Data is written into the memory when Read Enable (RE) is at logic "0" and read from the memory when RE is at logic "1".

### PIN CONFIGURATION



### LOGIC DIAGRAM



**SIGNETICS 64-BIT READ/WRITE MEMORY (RAM) ■ N7489**

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>See 8225 Data Sheet for Pin-for-Pin Replacement</b>					



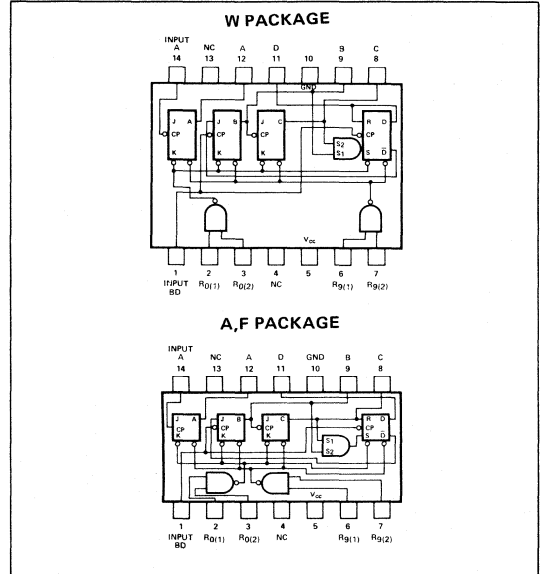
### DESCRIPTION

The S5490/N7490 is a high-speed, monolithic decade counter consisting of four dual-rank, master-slave flip-flops internally interconnected to provide a divide-by-two counter and a divide-by-five counter. Gated direct reset lines are provided to inhibit count inputs and return all outputs to a logical "0" or to a binary coded decimal (BCD) count of 9. As the output from flip-flop A is not internally connected to the succeeding stages, the count may be separated in three independent count modes:

1. When used as a binary coded decimal decade counter, the BD input must be externally connected to the A output. The A input receives the incoming count, and a count sequence is obtained in accordance with the BCD count sequence truth table shown above. In addition to a conventional "0" reset, inputs are provided to reset a BCD 9 count for nine's complement decimal applications.
2. If a symmetrical divide-by-ten count is desired for frequency synthesizers or other applications requiring division of a binary count by a power of ten, the D output must be externally connected to the A input. The input count is then applied at the BD input and a divide-by-ten square wave is obtained at output A.
3. For operation as a divide-by-two counter and divide-by-five counter, no external interconnections are required. Flip-flop A is used as a binary element for the divide-by-two function. The BD input is used to obtain binary divide-by-five operation at the B, C, and D outputs. In this mode, the two counters operate independently; however, all four flip-flops are reset simultaneously.

The 5490/7490 is completely compatible with Series 54 and Series 74 logic families. Average power dissipation is 160mW.

### PIN CONFIGURATIONS



### LOGIC TRUTH TABLES

BCD COUNT SEQUENCE (See Note 1)

COUNT	OUTPUT			
	D	C	B	A
0	0	0	0	0
1	0	0	0	1
2	0	0	1	0
3	0	0	1	1
4	0	1	0	0
5	0	1	0	1
6	0	1	1	0
7	0	1	1	1
8	1	0	0	0
9	1	0	0	1

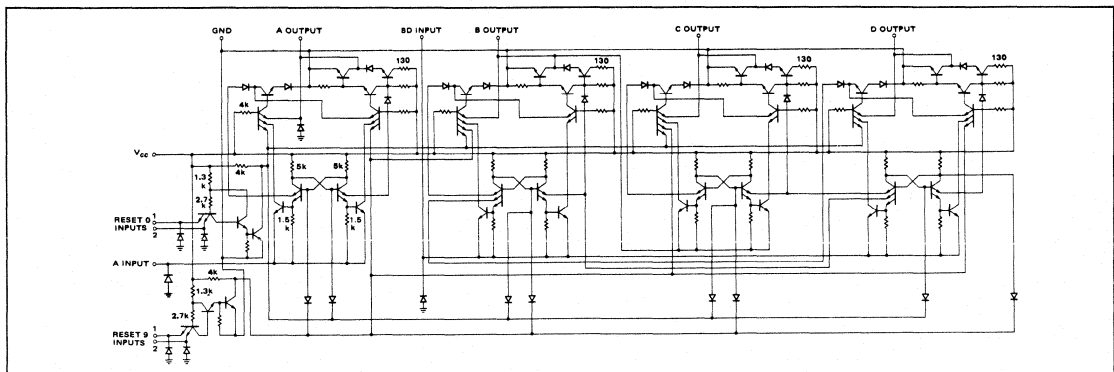
RESET/COUNT (See Note 2)

RESET INPUTS				OUTPUT			
R <sub>0</sub> (1)	R <sub>0</sub> (2)	R <sub>9</sub> (1)	R <sub>9</sub> (2)	D	C	B	A
1	1	0	X	0	0	0	0
1	1	X	0	0	0	0	0
X	X	1	1	1	0	0	1
X	0	X	0	COUNT			
0	X	0	X	COUNT			
0	X	X	0	COUNT			
X	0	0	X	COUNT			

#### NOTES:

1. Output A connected to input BD for BCD count.
2. X indicates that either a logical 1 of a logical 0 may be present.
3. Fanout from output A to input BD and to 10 additional Series 54/74 loads is permitted

### SCHEMATIC DIAGRAM



# SIGNETICS DECADE COUNTER ■ S5490, N7490

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5490 Circuits	4.5	5	5.5	V
N7490 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Width of Input Count Pulse, $t_p(\text{in})$	50			ns
Width of Reset Pulse, $t_p(\text{reset})$	50			ns
Operating Free-Air Temperature Range, $T_A$ : S5490 Circuits	-55	25	125	°C
N7490 Circuits	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V	
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V	
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -400\mu\text{A}$	2.4			V	
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 16\text{mA}$			0.4	V	
$I_{in(1)}$ Logical 1 level input current at $R_0(1)$ , $R_0(2)$ , $R_9(1)$ , or $R_9(2)$	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA	
$I_{in(1)}$ Logical 1 level input current at input A	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA	
$I_{in(1)}$ Logical 1 level input current at input BD	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			160 1	$\mu\text{A}$ mA	
$I_{in(0)}$ Logical 0 level input current at $R_0(1)$ , $R_0(2)$ , $R_9(1)$ , or $R_9(2)$	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA	
$I_{in(0)}$ Logical 0 level input current at input A	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA	
$I_{in(0)}$ Logical 0 level input current at input BD	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-6.4	mA	
$I_{OS}$ Short circuit output current †	$V_{CC} = \text{MAX}$ , $V_{out} = 0\text{V}$	S5490 N7490	-20 -18	-57 -57	mA mA	
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$	S5490 N7490		32 32	46 53	mA mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{max}}$ Maximum frequency of input count pulses	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	18		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from input count pulse to output C	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		60	100	ns
$t_{pd0}$ Propagation delay time to logical 0 level from input count pulse to output C	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		60	100	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

S5491-A,F,W • N7491-A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The S5491/N7491 is a monolithic serial-in, serial-out 8-bit shift register utilizing high-speed transistor-transistor logic (TTL) circuits. The shift register, composed of eight R-S master-slave flip-flops, includes input gating and a clock driver. The register is capable of storing and transferring data at clock rates up to 18 MHz while maintaining a typical noise-immunity level of 1 volt. Power dissipation is typically 175 milliwatts, and full fan-out of 10 is available from the outputs.

Single-rail data and input control are gated through inputs A and B and an internal inverter to form the complementary inputs to the first bit of the shift register. Drive for the internal common clock line is provided by an inverting clock driver. Each of the inputs (A, B, and  $\overline{CP}$ ) appear as only one TTL input load.

The clock pulse inverter/driver causes the S5491/N7491 to shift information to the output on the positive edge of an input clock pulse, thus enabling the shift-register to be fully compatible with the S5470/N7470 flip-flop and the S5474/N7474 dual D-type flip-flop.

### TRUTH TABLE

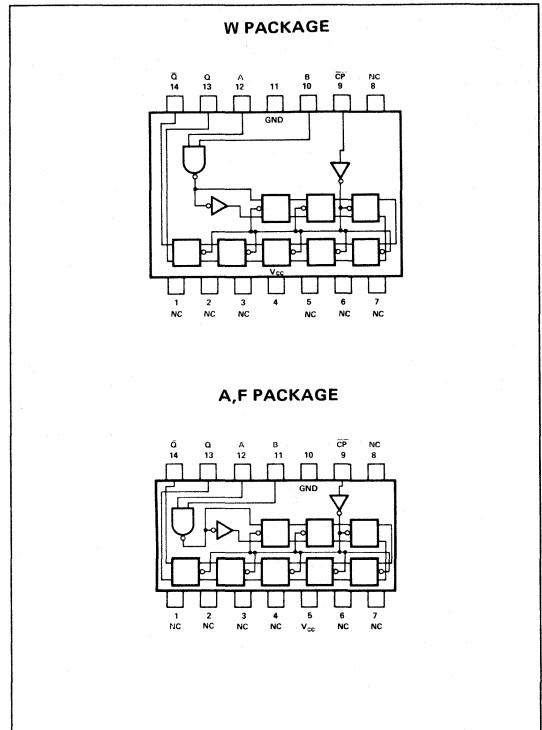
#### LOGIC

$t_n$		$t_{n+8}$
A	B	Q
0	0	0
0	1	0
1	0	0
1	1	1

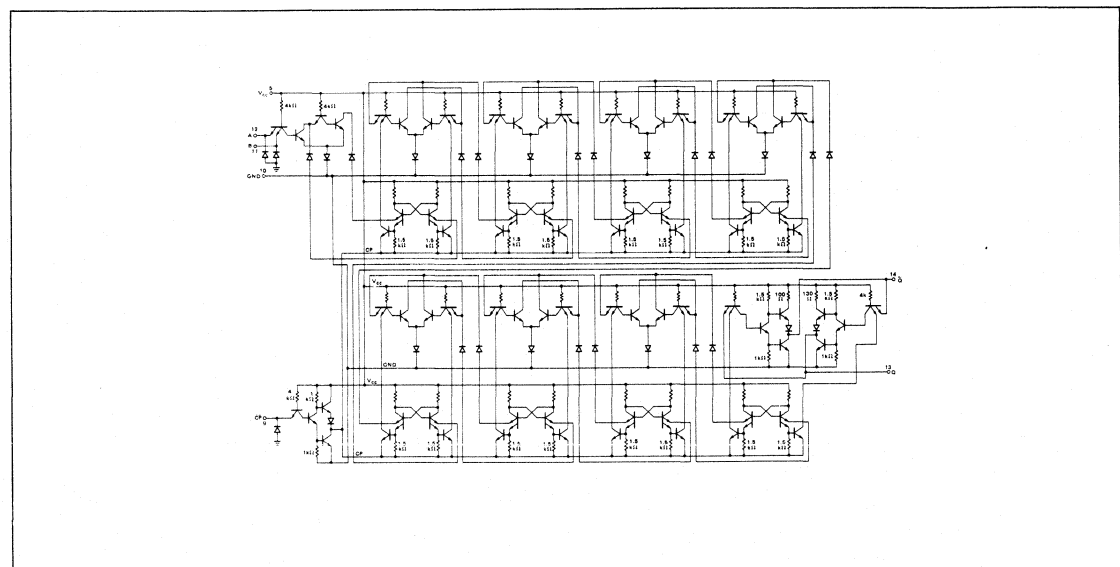
#### NOTES:

- $t_n$  = bit time before clock pulse.
- $t_{n+8}$  = bit time after 8 clock pulse.

### PIN CONFIGURATIONS



### SCHEMATIC DIAGRAM



# SIGNETICS 8-BIT SHIFT REGISTER ■ S5491, N7491

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5491 Circuits N7491 Circuits	4.5	5	5.5	V
	4.75	5	5.25	V
Normalized Fan-Out from each Output, N Operating Free-Air Temperature Range, $T_A$ : S5491 Circuits N7491 Circuits	-55	25	125	°C
	0	25	70	°C
Width of Clock Pulse, $t_{p(\text{clock})}$	25			ns
Input Setup Time, $t_{\text{setup}}$	25			ns
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal $V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal $V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}$ , $I_{\text{load}} = -400\mu\text{A}$	2.4	3.5		V
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 16\text{mA}$		0.22	0.4	V
$I_{in(0)}$	Logical 0 level input current $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(1)}$	Logical 1 level input current $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current † $V_{CC} = \text{MAX}$ , $V_{out} = 0$	S5491 N7491	-20 -18	-57 -57	mA mA
$I_{CC}$	Supply current $V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$	S5491 N7491	35 35	50 58	mA mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , $N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{max}}$	Maximum shift frequency $C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	18		MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output $C_L = 15\text{pF}$ , $R_L = 400\Omega$		24	40	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output $C_L = 15\text{pF}$ , $R_L = 400\Omega$		27	40	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

S5492-A,F,W • N7492-A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The S5492/N7492 is a high-speed monolithic 4-bit binary counter consisting of four master-slave flip-flops which are internally interconnected to provide a divide-by-two counter and a divide-by-six counter. A gated direct reset line is provided which inhibits the count inputs and simultaneously returns the four flip-flops outputs to a logical 0. As the output from flip-flop A is not internally connected to the succeeding flip-flops the counter may be operated in two independent modes:

1. When used as a divide-by-twelve counter, output A must be externally connected to input BC. The input count pulses are applied to input A. Simultaneous division of 2, 6, and 12 are performed at the A, C, and D outputs as shown in the truth table.
2. When used as a divide-by-six counter, the input count pulses are applied to input BC. Simultaneously, frequency division of 3 and 6 are available at the C and D outputs. Independent use of flip-flop A is available if the reset function coincides with reset of the divide-by-six counter.

The S5492/N7492 is completely compatible with Series 54 and Series 74 logic families. Average power dissipation is 155mW.

### TRUTH TABLE (See Notes 1 and 2)

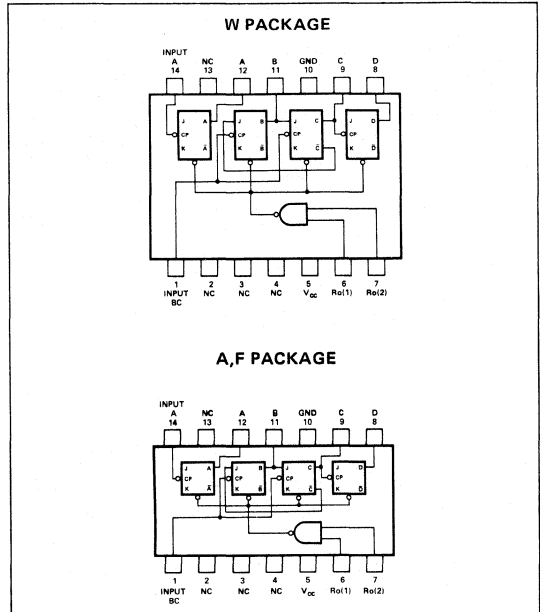
COUNT	OUTPUT			
	D	C	B	A
0	0	0	0	0
1	0	0	0	1
2	0	0	1	0
3	0	0	1	1
4	0	1	0	0
5	0	1	0	1

COUNT	OUTPUT			
	D	C	B	A
6	1	0	0	0
7	1	0	0	1
8	1	0	1	0
9	1	0	1	1
10	1	1	0	0
11	1	1	0	1

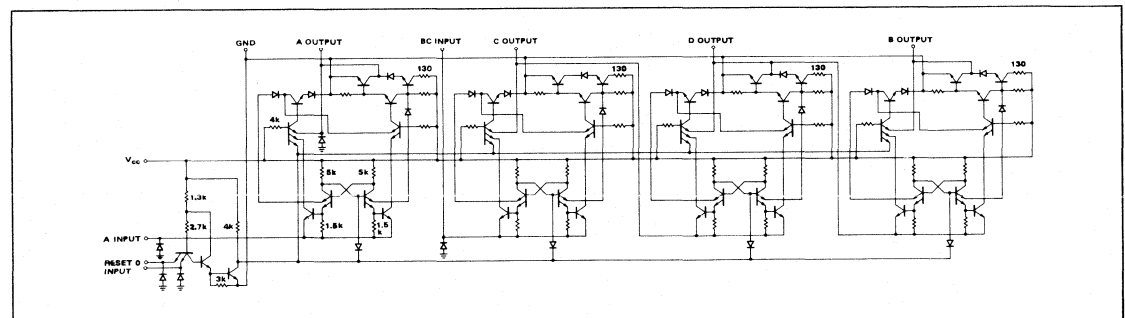
### NOTES:

1. Output A connected to input B.
2. To reset all outputs to logical 0, both R<sub>0(1)</sub> and R<sub>0(2)</sub> inputs must be at logical 1.

### PIN CONFIGURATIONS



### SCHEMATIC DIAGRAM





**SIGNETICS DIVIDE-BY-TWELVE COUNTER ■ S5492, N7492**

**RECOMMENDED OPERATING CONDITIONS**

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5492 Circuits	4.5	5	5.5	V
N7492 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S5492 Circuits	-55	25	125	°C
N7492 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Input Count Pulse, $t_{p(in)}$	50			ns
Width of Reset Pulse, $t_{p(reset)}$	50			ns

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal $V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal $V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	2.4			V
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$			0.4	V
$I_{in(1)}$	Logical 1 level input current at $R_{Q(1)}$ or $R_{Q(2)}$ inputs $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at input A $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at input BC $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			160 1	$\mu\text{A}$ mA
$I_{in(0)}$	Logical 0 level input current at $R_{Q(1)}$ or $R_{Q(2)}$ inputs $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$	Logical 0 level input current input A $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(0)}$	Logical 0 level input current at input BC $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-6.4	mA
$I_{OS}$	Short circuit output current † $V_{CC} = \text{MAX}$ , $V_{out} = 0$	S5492 N7492	-20 -18	-57 -57	mA mA
$I_{CC}$	Supply current $V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$	S5492 N7492	* 31 31	44 51	mA mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ , N = 10**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum frequency of input count pulses $C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	18		MHz
$t_{pd1}$	Propagation delay time to logical 1 level from input count pulse to output D $C_L = 15\text{pF}$ , $R_L = 400\Omega$		60	100	ns
$t_{pd0}$	Propagation delay time to logical 0 level from input count pulse to output D $C_L = 15\text{pF}$ , $R_L = 400\Omega$		60	100	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

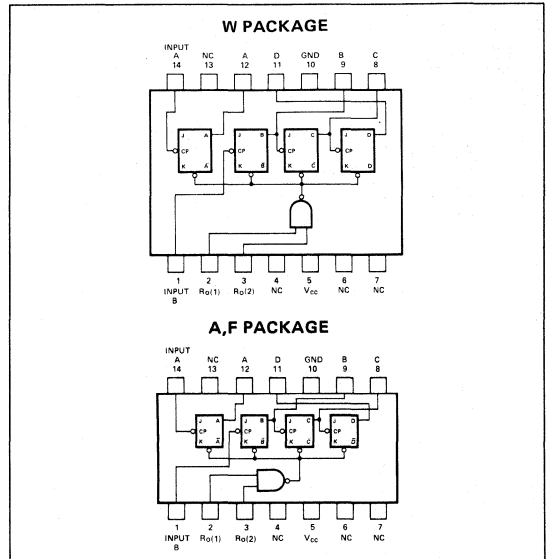
### DESCRIPTION

The S5493/N7493 is a high-speed, monolithic 4-bit binary counter consisting of four master-slave flip-flops which are internally interconnected to provide a divide-by-two counter and a divide-by-eight counter. A gated direct reset line is provided which inhibits the count inputs and simultaneously returns the four flip-flop outputs to a logical 0. As the output from flip-flop A is not internally connected to the succeeding flip-flops the counter may be operated in two independent modes:

1. When used as a 4-bit ripple-through counter output A must be externally connected to input B. The input count pulses are applied to input A. Simultaneous divisions of 2, 4, 8, and 16 are performed at the A, B, C, and D outputs as shown in the truth table.
2. When used as a 3-bit ripple-through counter, the input count pulses are applied to input B. Simultaneous frequency divisions of 2, 4, and 8 are available at the B, C, and D outputs. Independent use of flip-flop A is available if the reset function coincides with reset of the 3-bit ripple-through counter.

The S5493/N7493 is completely compatible with Series 54 and Series 74 logic families. Average power dissipation is 32mW per flip-flop (128mW total).

### PIN CONFIGURATIONS



### TRUTH TABLE (See Notes 1 and 2)

LOGIC				
COUNT	OUTPUT			
	D	C	B	A
0	0	0	0	0
1	0	0	0	1
2	0	0	1	0
3	0	0	1	1
4	0	1	0	0
5	0	1	0	1
6	0	1	1	0
7	0	1	1	1
8	1	0	0	0

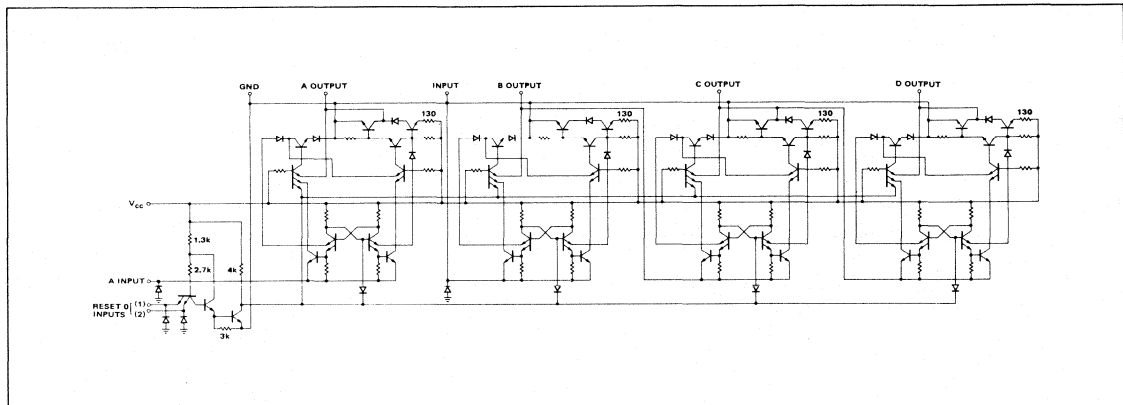
COUNT	OUTPUT			
	D	C	B	A
9	1	0	0	1
10	1	0	1	0
11	1	0	1	1
12	1	1	0	0
13	1	1	0	1
14	1	1	1	0
15	1	1	1	1

NOTES:

1. Output A connected to input B.
2. To reset all outputs to logical 0, both R<sub>0</sub>(1) and R<sub>0</sub>(2) inputs must be at logical 1.

### SCHEMATIC DIAGRAM



# SIGNETICS 4-BIT BINARY COUNTER ■ S5493, N7493

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S5493 Circuits	4.5	5	5.5	V
N7493 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S5493 Circuits	-55	25	125	°C
N7493 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Input Count Pulse, $t_{p(in)}$	50			ns
Width of Reset Pulse, $t_{p(reset)}$	50			ns

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -400\mu\text{A}$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 16\text{mA}$			0.4	V
$I_{in(1)}$ Logical 1 level input current at $R_0(1)$ or $R_0(2)$ inputs	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at A or B inputs	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			80 1	$\mu\text{A}$ mA
$I_{in(0)}$ Logical 0 level input current at $R_0(1)$ or $R_0(2)$ inputs	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at A or B inputs	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{OS}$ Short circuit output current†	$V_{CC} = \text{MAX}$ , $V_{out} = 0$	S5493 -20 N7493 -18		-57 -57	mA mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$	S5493 N7493	32 32	46 53	mA mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum frequency of input count pulses	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	18		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from input count pulse to output D	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		75	135	ns
$t_{pd0}$ Propagation delay time to logical 0 level from input count pulse to output D	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		75	135	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

This monolithic shift register, utilizing transistor-transistor logic (TTL) circuits in the familiar Series 74 configuration, is composed of four R-S master-slave flip-flops, four AND-OR-INVERT gates, and four inverter-drivers. Internal interconnections of these functions provide a versatile register which performs right-shift operations as a serial-in, serial-out register or as a dual-source, parallel-to-serial converter. A number of these registers may be connected in series to form an n-bit register.

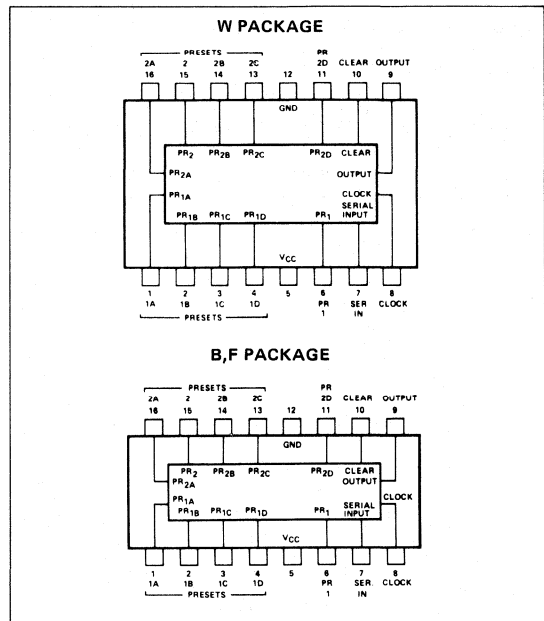
All flip-flops are simultaneously set to the logical 0 state by applying a logical 1 voltage to the clear input. This condition may be applied independent of the state of the clock input, but not independent of state of the preset input. Preset input is independent of the clock and clear states.

The flip-flops are simultaneously set to the logical 1 state from either of two preset input sources. Preset inputs 1A through 1D are activated during the time that a positive pulse is applied to preset 1 if preset 2 is at a logical 0 level. When the logic levels at preset 1 and preset 2 are reversed, preset inputs 2A through 2D are active.

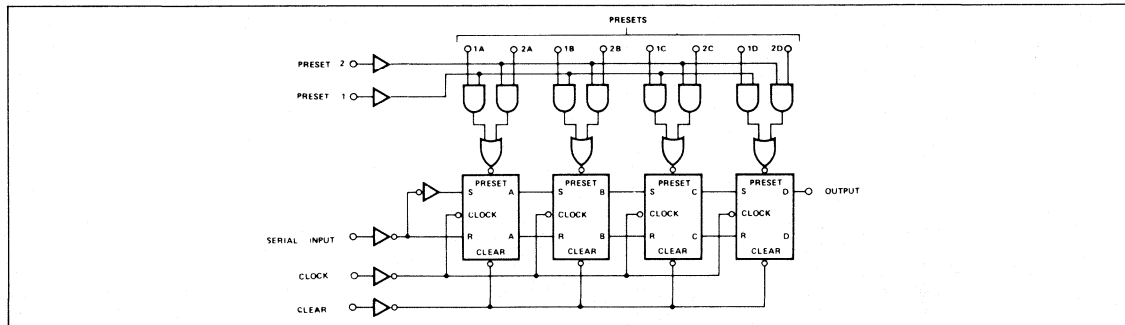
Transfer of information to the outputs occurs when the clock input goes from a logical 0 to a logical 1. Since the flip-flops are R-S master-slave circuits, the proper information must appear at the R-S inputs of each flip-flop prior to the rising edge of the clock input waveform. The serial input provides this information for the first flip-flop. The output of the subsequent flip-flops provide information for the remaining R-S inputs. The clear input, preset 1, and preset 2 must be at a logical 0 when clocking occurs.

This register is completely compatible for use with TTL and DTL logic circuits and when used with other TTL circuits, noise margins are typically one volt. Typical average power dissipation is 175 milliwatts, and propagation delay times from clock to output are typically 25 nanoseconds.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	TYP	MAX	UNIT
Supply Voltage $V_{CC}$	4.5	5	5.5	V
	4.75	5	5.25	V
Normalized Fan-Out From Each Output			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	35			ns
Width of Clear Pulse, $t_{p(\text{clear})}$	30			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	30			ns
Serial Input Setup Time: $t_{\text{setup}(1)}$	35			ns
	25			ns
Serial Input Hold Time, $t_{\text{hold}}$	0			

# SIGNETICS 4-BIT SHIFT REGISTER (PARALLEL-IN, SERIAL-OUT) ■ S5494, N7494

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{load} = -400 \mu\text{A}$	2.4	3.5		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{sink} = 16\text{mA}$		0.22	0.4	V
$I_{in(1)}$	Logical 1 level input current at any input except preset 1 and preset 2	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			40 1	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at preset 1 and preset 2	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			160 1	$\mu\text{A}$ mA
$I_{in(0)}$	Logical 0 level input current at any input except preset 1 and preset 2	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$	Logical 0 level input current at preset 1 and preset 2	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-6.4	mA
$I_{OS}$	Short-circuit input current†	$V_{CC} = \text{MAX}, V_{out} = 0$	-20 -18		-57 -57	mA mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$		35 35	50 58	mA mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$f_{max}$	Maximum clock frequency	$C_L = 15\text{pF}$	$R_L = 400\Omega$	10			MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output to output	$C_L = 15\text{pF}$	$R_L = 400\Omega$		25	40	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output	$C_L = 15\text{pF}$	$R_L = 400\Omega$		25	40	ns
$t_{pd1}$	Propagation delay time to logical 1 level from preset to output	$C_L = 15\text{pF}$	$R_L = 400\Omega$			35	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clear to output	$C_L = 15\text{pF}$	$R_L = 400\Omega$			40	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

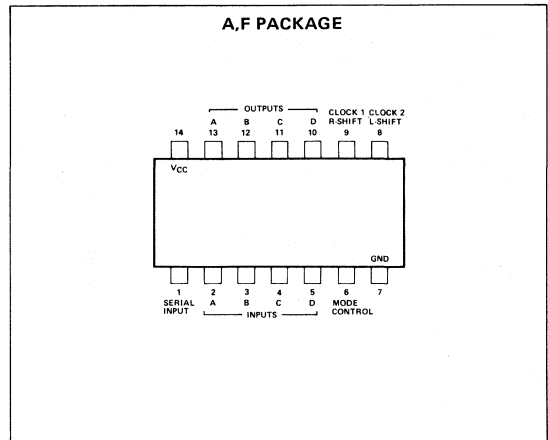
The 54/7495 is a monolithic universal 4-Bit Shift Register designed with standard TTL techniques. The circuit layout consists of 4 R-S master-slave flip-flops, 4 AND-OR-INVERT gates, and 6 inverters configured to form a versatile register which will perform right-shift, left-shift, or parallel-in, parallel-out operations depending on the logical input level to the mode control.

Right-shift operations are performed when a logical 0 level is applied to the mode control. Serial data is entered at the serial input  $D_S$  and shifted one position right on each clock 1 pulse. In this mode, clock 2 and parallel inputs  $D_A$  thru  $D_D$  are inhibited.

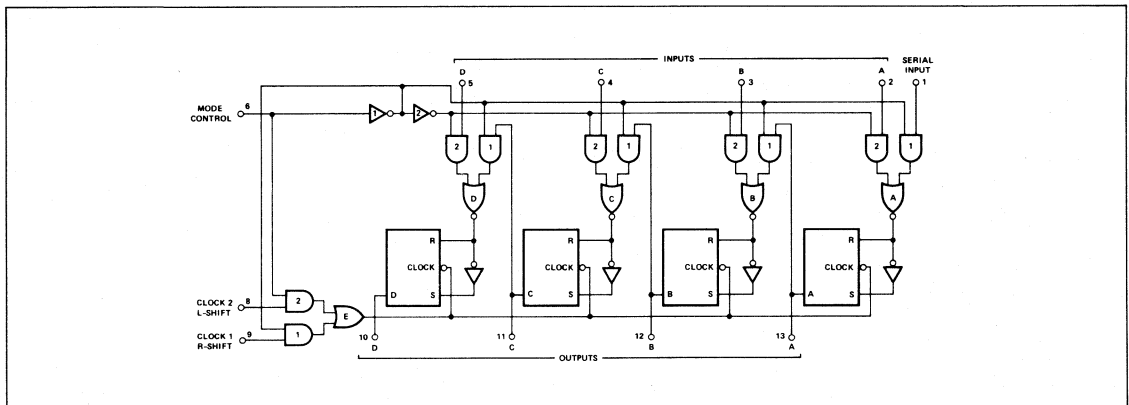
Parallel-in, parallel-out operations are performed when a logical 1 level is applied to the mode control. Parallel data is entered at parallel inputs  $D_A$  thru  $D_D$  and is transferred to the data outputs  $A_Q$  thru  $D_Q$  on each clock 2 pulse. In this mode, shift-left operations may be implemented by externally tying the output of each flip-flop to the parallel input of the previous flip-flop ( $D_0$  to  $D_C$  and etc.), with serial data entry at input  $D_D$ .

Information must be present at the R-S inputs prior to clocking and transfer of data occurs on the falling edge of the clock pulse.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$	4.5	5	5.5	V
	4.75	5	5.25	V
Normalized Fan-Out From Each Output			10	
Width of Clock Pulse $t_{p(\text{clock})}$	20	10		ns
Setup Time Required at Serial, A, B, C, or D Inputs $t_{\text{setup}}$	15	10		ns
Hold Time Required at Serial, A, B, C, or D Inputs $t_{\text{hold}}$	10	10		ns
Logical 0 Level Setup Time Required at Mode Control (With Respect to Clock 1 inputs)	0	10		ns
Logical 1 level Setup Time Required at Mode Control (With Respect to Clock 2 input)	15			ns
Logical 0 Level Setup Time Required at Mode Control (With Respect to Clock 2 input)	15			ns
Logical 1 Level Setup Time Required at Mode Control (With Respect to Clock 1 input)	5			ns
Logical 1 Level Setup Time Required at Mode Control (With Respect to Clock 1 input)	5			ns

# SIGNETICS 4-BIT RIGHT-SHIFT LEFT-SHIFT REGISTER ■ S5495, N7495

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{load} = -80\mu\text{A}$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{sink} = 16\text{mA}$			0.4	V
$I_{in(0)}$	Logical 0 level input current at any input except mode control	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$	Logical 0 level input current at mode control	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(1)}$	Logical 1 level input current at any input except mode control	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			40	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$	Logical 1 level input current at mode control	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			80	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX}$	-18		-57	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ N7495	39	50	63	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$f_{max}$	Maximum shift frequency	$C_L = 15\text{pF},$	$R_L = 400\Omega$	25	36		MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clock 1 or clock 2 to outputs	$C_L = 15\text{pF},$	$R_L = 400\Omega$		18	27	ns
	Propagation delay time to logical 0 level from clock 1 or clock 2 to outputs				21	32	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

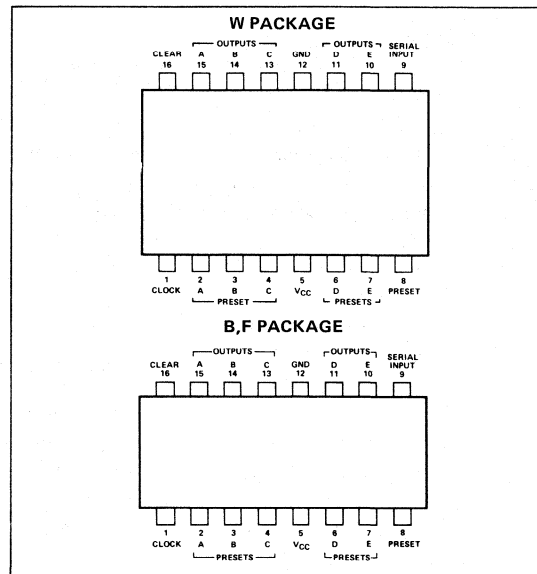
This shift register consists of five R-S master-slave flip-flops connected to perform parallel-to-serial or serial-to-parallel conversion of binary data. Since both inputs and outputs to all flip-flops are accessible, parallel-in/parallel-out or serial-in/serial-out operation may be performed.

All flip-flops are simultaneously set to the logical 0 state by applying a logical 0 voltage to the clear input. This condition may be applied independent of the state of the clock input.

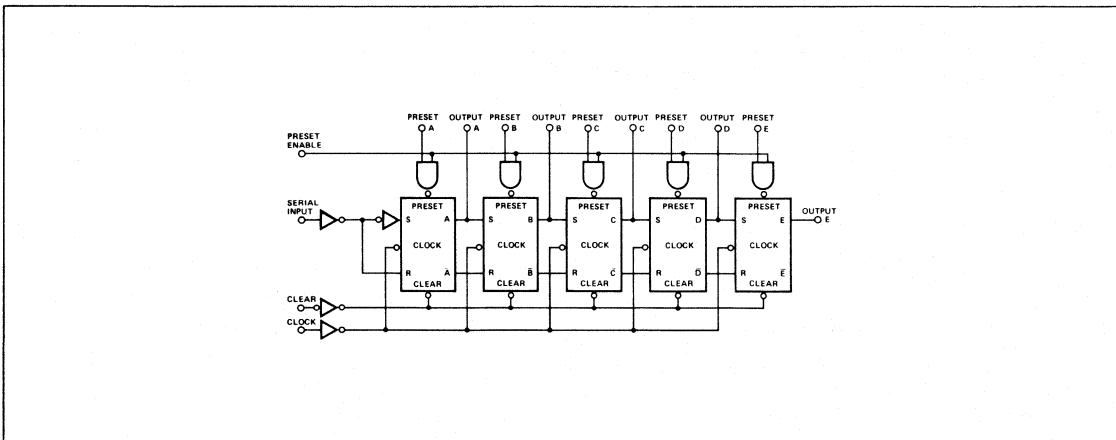
The flip-flops may be independently set to the logical 1 state by applying a logical 1 to both the preset input of the specific flip-flop and the common preset input. The common preset input is provided to allow flexibility of either setting each flip-flop independently or setting two or more flip-flops simultaneously. Preset is also independent of the state of the clock input or clear input.

Transfer of information to the output pins occurs when the clock input goes from a logical 0 to a logical 1. Since the flip-flops are R-S master-slave circuits, the proper information must appear at the R-S inputs of each flip-flop prior to the rising edge of the clock input voltage waveform. The serial input provides this information to the first flip-flop, while the outputs of the subsequent flip-flops provide information for the remaining R-S inputs. The clear input must be at a logical 1 and the preset input must be at a logical 0 when clocking occurs.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	TYP	MAX	UNIT
Supply Voltage $V_{CC}$	4.5	5	5.5	V
Normalized Fan-Out from Output	4.75	5	5.25	V
Width of Clock Pulse, $t_p(\text{clock})$	35		10	ns
Width of Clear Pulse, $t_p(\text{clear})$	30			ns
Width of Preset Pulse, $t_p(\text{preset})$	30			ns
Serial Input Setup Time, $t_{\text{setup}}$	30			ns
Serial Input Hold Time, $t_{\text{hold}}$	0			ns



SIGNETICS 5-BIT SHIFT REGISTER ■ S5496, N7496

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$		2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -400\mu\text{A}$		2.4	3.5		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 16\text{mA}$			0.22	0.4	V
$I_{in(1)}$	Logical 1 level input current at any input except preset (pin ⑧)	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$				40	$\mu\text{A}$
						1	mA
$I_{in(1)}$	Logical 1 level input current at preset (pin ⑧)	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$				200	$\mu\text{A}$
						1	mA
$I_{in(0)}$	Logical 0 level input current at any input except preset (pin ⑧)	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$				-1.6	mA
$I_{in(0)}$	Logical 0 level input current at preset (pin ⑧)	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$				-8	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX}, V_{out} = 0$	S5496	-20		-57	mA
			N7496	-18		-57	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$	S5496		48	68	mA
			N7496		48	79	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$f_{\text{max}}$	Maximum clock frequency	$C_L = 15\text{pF}, R_L = 400\Omega$		10			MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output	$C_L = 15\text{pF}, R_L = 400\Omega$			25	40	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output	$C_L = 15\text{pF}, R_L = 400\Omega$			25	40	ns
$t_{pd1}$	Propagation delay time to logical 1 level from preset to output	$C_L = 15\text{pF}, R_L = 400\Omega$				35	ns
$t_{pd0}$	Propagation delay time to logical 0 level from preset to output	$C_L = 15\text{pF}, R_L = 400\Omega$			28	40	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clear to output	$C_L = 15\text{pF}, R_L = 400$				55	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

#### DESCRIPTION

These latches are ideally suited for use as temporary storage for binary information between processing units and input/output or indicator units. Information present at a data (D) input is transferred to the Q output when the clock is high, and the Q output will follow the data input as long as the clock remains high. When the clock goes low, the information (that was present at the data input at the time the transition occurred) is retained at the Q output until the clock is permitted to go high.

The S54100/N74100 features two independent quadruple latches in a single 24-pin dual in-line package. These circuits are completely compatible with all popular TTL or DTL families. Typical power dissipation is 40 milliwatts per latch. The Series 54 circuits are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$  and Series 74 circuits are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### ABSOLUTE MAXIMUM RATINGS (over operating temperature range unless otherwise noted)

Supply Voltage, $V_{CC}$ (See Note 3)	7V
Input Voltage, $V_{in}$ (See Notes 3 and 4)	5.5V
Operating Free-Air Temperature Range:	
S54100 Circuits	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
N74100 Circuits	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

#### NOTES:

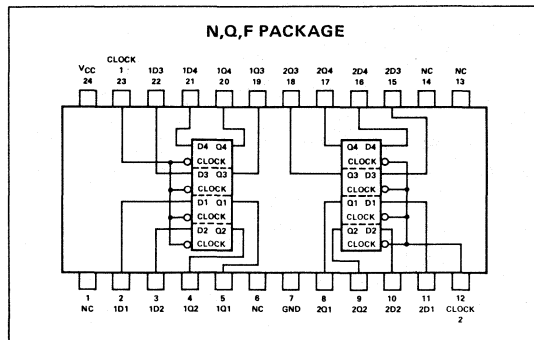
- These voltage values are with respect to network ground terminal.
- Input signals must be zero or positive with respect to network ground terminal.

#### TRUTH TABLE

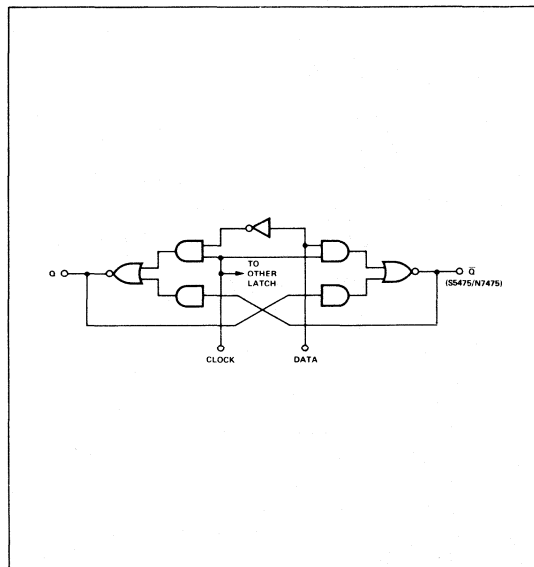
LOGIC (Each Latch)		NOTES:
$t_n$ D	$t_{n+1}$ Q	
1	1	<ol style="list-style-type: none"> <li><math>t_n</math> = bit time before clock negative-going transition.</li> <li><math>t_{n+1}</math> = bit time after clock negative-going transition.</li> </ol>
0	0	

NC — No internal connection.

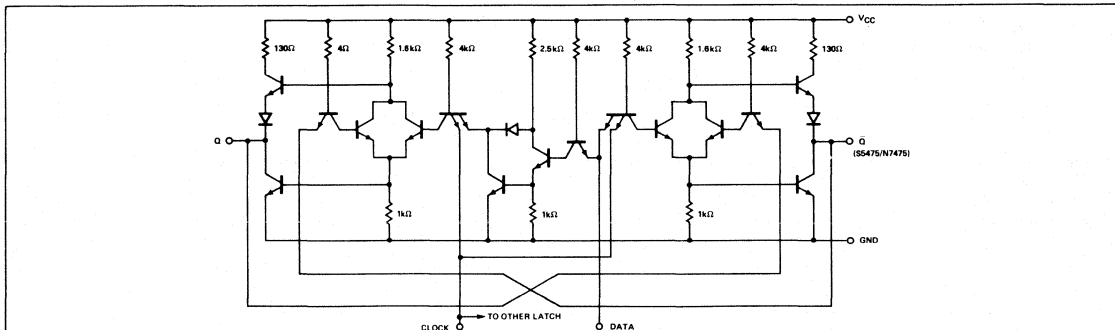
#### PIN CONFIGURATIONS



#### LOGIC DIAGRAM (each latch)



#### SCHEMATIC DIAGRAM (each latch)



NOTE: Component values shown are nominal.

# SIGNETICS 4-BIT BISTABLE LATCH ■ S54100, N74100

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ (See Note 3):	S54100 N74100	4.5 4.75	5 5	5.5 5.25 10	V V
Normalized Fan-Out from Output					

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT	
$V_{in(1)}$	Input voltage required to ensure logical 1 level at any input terminal	2			V	
$V_{in(0)}$	Input voltage required to ensure logical 0 level at any input terminal			0.8	V	
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{load} = -400\mu\text{A}$	2.4		V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{sink} = 16\text{mA}$		0.4	V	
$I_{in(0)}$	Logical 0 level input current at D	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$		-3.2	mA	
$I_{in(0)}$	Logical 0 level input current at clock	$V_{CC} = \text{MAX}, S54100, N74100$		-12.8	mA	
$I_{in(1)}$	Logical 1 level input current at D	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$		80	$\mu\text{A}$	
	Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$		1	mA	
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}, S54100, N74100$		160	$\mu\text{A}$	
		$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}, S54100, N74100$		320	$\mu\text{A}$	
		$V_{CC} = \text{MAX}, V_{out} = 0, S54100, N74100$		1	mA	
$I_{OS}$	Short-circuit output current	$V_{CC} = \text{MAX}, V_{out} = 0, S54100, N74100$		-20	-57	mA
				-18	-57	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, S54100, N74100$		64	92	mA
				64	106	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS NOTE A	MIN	TYP	MAX	UNIT
$t_{pd1(D-Q)}$	Propagation delay time to logical 1 level from D input to Q output	$C_L = 15\text{pF}, R_L = 400\Omega$	16	30	ns
$t_{pd0(D-Q)}$	Propagation delay time to logical 0 level from D input to Q output	$C_L = 15\text{pF}, R_L = 400\Omega$	14	25	ns
$t_{pd1(C-Q)}$	Propagation delay time to logical 1 level from clock input to Q output	$C_L = 15\text{pF}, R_L = 400\Omega$	16	30	ns
$t_{pd0(C-Q)}$	Propagation delay time to logical 0 level from clock input to Q output	$C_L = 15\text{pF}, R_L = 400\Omega$	7	15	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

‡ These typical times indicate that period occurring prior to the fall of clock pulse ( $t_G$ ) below 1.5V when data at the D input will still be recognized and stored.

NOTE A: AC Test circuit, voltage waveforms and switching times are given on p. 2-76.

S54107-A,F • N74107-A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The S54107A/N74107A J-K flip-flop is based on the master-slave principle. Inputs to the master section are controlled by the clock pulse. The clock pulse also regulates the state of the coupling transistors which connect the master and slave sections. The sequence of operation is as follows:  
See S5473/N7473 waveform.

1. Isolate slave from master
2. Enter information from J and K inputs to master
3. Disable J and K inputs
4. Transfer information from master to slave.

### TRUTH TABLE

#### LOGIC

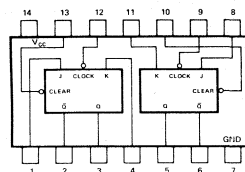
(Each Flip-Flop)		
$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

#### NOTES:

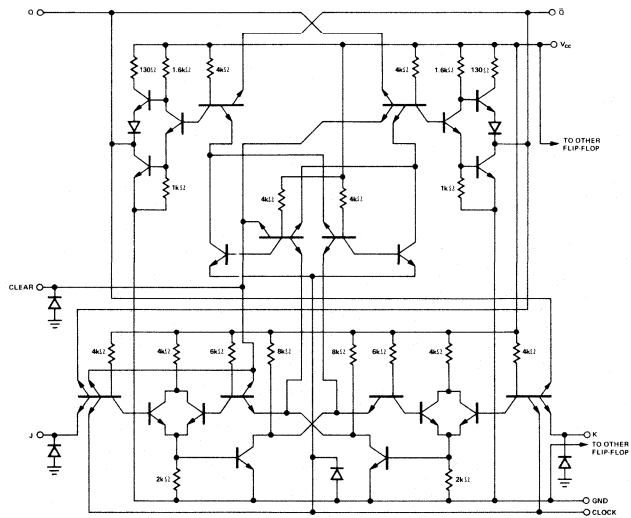
1.  $t_n$  = bit time before clock pulse.
2.  $t_{n+1}$  = bit time after clock pulse.

### PIN CONFIGURATIONS

#### A,F PACKAGE



### SCHEMATIC (each flip-flop)



NOTE: Component values shown are nominal.

# SIGNETICS DUAL J-K MASTER-SLAVE FLIP-FLOP ■ S54107, N74107

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54107 Circuits	4.5	5	5.5	V
N74107 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54107 Circuits	-55	25	125	°C
N74107 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $p(\text{clock})$	20			ns
Width of Clear Pulse, $t_p(\text{clear})$	25			ns
Input Setup Time, $t_{\text{setup}}$	$\geq t_p(\text{clock})$			
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -400\mu\text{A}$	2.4	3.5		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 16\text{mA}$		0.22	0.4	V
$I_{in(0)}$ Logical 0 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-1.6	mA
$I_{in(0)}$ Logical 0 level input current at clear or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-3.2	mA
$I_{in(1)}$ Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$			40	$\mu\text{A}$
	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$ Logical 1 level input current at clear or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$			80	$\mu\text{A}$
	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			1	mA
$I_{OS}$ Short circuit output current†	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	S54107 N74107	-20 -18	-57 -57	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 5\text{V}$			20 40	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{\text{clock}}$ Maximum clock frequency	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	15	20		MHz
$t_{\text{pd1}}$ Propagation delay time to logical 1 level from clear to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		16	25	ns
$t_{\text{pd0}}$ Propagation delay time to logical 0 level from clear to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$		25	40	ns
$t_{\text{pd1}}$ Propagation delay time to logical 1 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	16	25	ns
$t_{\text{pd0}}$ Propagation delay time to logical 0 level from clock to output	$C_L = 15\text{pF}$ , $R_L = 400\Omega$	10	25	40	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

These J-K positive-edge-triggered flip-flops feature a buffered clock input, direct preset and clear, and J and K inputs. The clock buffer offers typical TTL high noise immunity, low clock-line loading, and in most cases eliminates the need for stringent control of system-clock rise and fall times. When activated, the direct preset and clear inputs control the state of the flip-flop outputs independently of the clock and synchronous-input levels. The J and K data inputs simplify hardware design as a D-type flip-flop can be implemented by simply tying the J and K inputs together.

Due to the internal clock buffer the J and K inputs accept data when the clock line is low, and transfer of data occurs during the clock-line transition from the low level to the high level. Following the hold time interval, data at the J and K inputs may be changed when the clock is either high or low without affecting the state of the output. Data meeting the setup time requirements will be transferred on the positive-going clock transition.

These TTL circuits feature one-volt typical d-c noise margins and are compatible for use with most TTL and DTL families. Full fan-out to 20 high-level and 10 low-level normalized Series 54/74 loads is available from each output. The 54109 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 74109 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### FUNCTION TABLE

INPUTS AT $t_n$		OUTPUTS AT $t_{n+1}$	
J	K	Q	$\bar{Q}$
L	H	$Q_n$	$Q_n$
L	L	L	H
H	H	H	L
H	L	$\bar{Q}_n$	$\bar{Q}_n$

$t_n$  = bit time before clock pulse

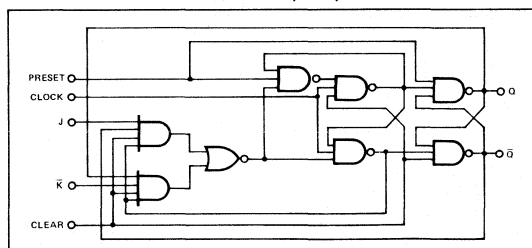
$t_{n+1}$  = bit time after clock pulse

H = high level, L = low level

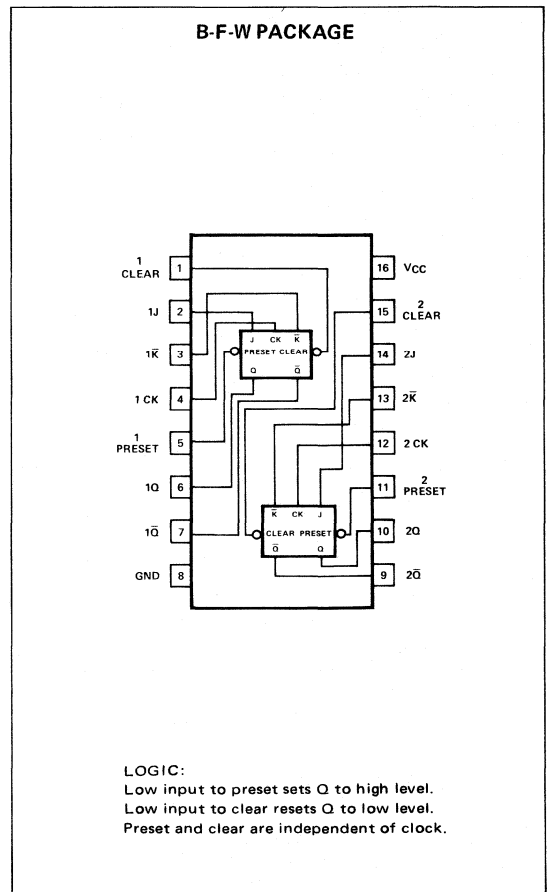
$Q_n$  = level of output Q at  $t_n$

$\bar{Q}_n$  = complement of  $Q_n$  or level of output  $\bar{Q}$  at  $t_n$

### BLOCK DIAGRAM (each flip-flop)



### PIN CONFIGURATIONS



**ABSOLUTE MAXIMUM RATINGS** Over operating free-air temperature range. Unless otherwise noted.

Supply Voltage, $V_{CC}$ (See Note 1)	7 V
Input Voltage (See Note 1)	5.5 V
Interemitter Voltage (See Note 2)	5.5 V
Operating Free-Air Temperature Range:	
54109 Circuits	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
74109 Circuits	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

#### NOTES:

- Voltage values except interemitter voltage are with respect to network ground terminal.
- This is the voltage between two emitters of a multiple-emitter transistor. For this circuit, this rating applies between the clear input and the clock, J, or K input.

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		54109			74109			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level			20			20	
	Low logic level			10			10	
Width of low- or high-level clock pulse, $t_w(\text{clock})$		20			20			ns
Width of preset of clear pulse, $t_w(\text{preset})$ or $t_w(\text{clear})$		20			20			ns
Input setup time, $t_{\text{setup}}$ (see Figure 1)		10			10			ns
Input hold time, $t_{\text{hold}}$ (see Figure 1)		6			6			ns
Operating free-air temperature, $T_A$		-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS Over recommended operating free-air temperature range. Unless otherwise noted.

PARAMETER		TEST CONDITIONS <sup>1</sup>	MIN	TYP <sup>2</sup>	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$			-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_{OH} = -800\ \mu\text{A}$	2.4	2.7		V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, I_{OL} = 16\text{mA}$		0.2	0.4	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$	J or $\bar{K}$ input	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			40	$\mu\text{A}$
	Clock or preset				80	
	Clear				160	
$I_{IL}$	J or $\bar{K}$ input	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$			-1.6	mA
	Clock or preset				-3.2	
	Clear				-4.8	
$I_{OS}$	Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX}$	30		85	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$			30	mA
		$V_{CC} = 5\text{V}$ See Note 3			28	mA

## NOTES

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

2. All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

3. Only one output should be shorted at a time.

NOTE 3:  $I_{CC}$  is measured with presets at 4.5V, all other inputs grounded, and outputs open.

SWITCHING CHARACTERISTICS  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

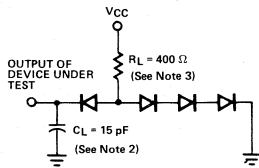
PARAMETER <sup>1</sup>	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Clock	Q or $\bar{Q}$	$C_L = 15\text{pF}$ , $R_L = 400\ \Omega$ See Figure 1	4	10	16	ns
$t_{PHL}$				9	18	28	
$t_{PLH}$	Preset	Q			10	15	ns
$t_{PHL}$		$\bar{Q}$			23	35	
$t_{PLH}$	Clear	$\bar{Q}$			10	15	ns
$t_{PHL}$		Q			17	25	

<sup>1</sup> $t_{PLH}$  ≡ Propagation delay time, low-to-high-level output

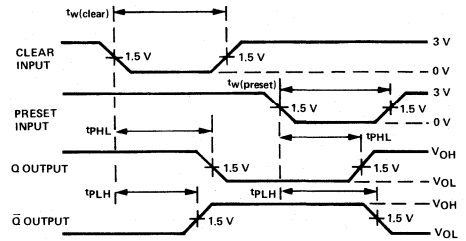
$t_{PHL}$  ≡ Propagation delay time, high-to-low-level output

PARAMETER MEASUREMENT INFORMATION

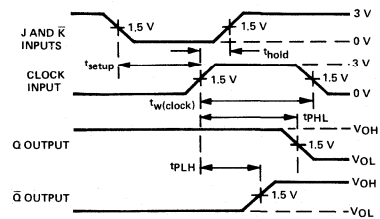
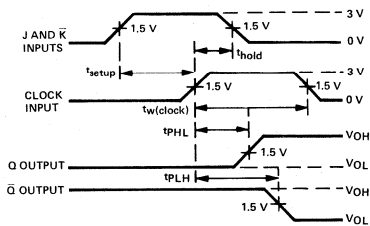
LOAD CIRCUIT



PROPAGATION DELAY TIMES FROM CLEAR AND PRESET



PROPAGATION DELAY TIMES FROM CLOCK



NOTES

1. Input pulses are supplied by generators having the following characteristics:  $t_{TLH} \leq 10\text{ns}$ ,  $t_{THL} \leq 10\text{ns}$ ,  $\text{PRR} = 1 \text{ MHz}$ ,  $Z_{out} \approx 50\Omega$ .
2.  $C_L$  includes probe and jig capacitance.
3. All diodes 1N3064.



#### DESCRIPTION

This monolithic TTL monostable multivibrator features d-c triggering from positive or gated negative-going inputs with inhibit facility. Both positive and negative-going output pulses are provided with full fan-out to 10 normalized loads.

Pulse triggering occurs at a particular voltage level and is not directly related to the transition time of the input pulse. Schmitt-trigger input circuitry for the B input allows jitter-free triggering from inputs with transition times as slow as 1 volt/second, providing the circuit with an excellent noise immunity of typically 1.2 volts. A high immunity to  $V_{CC}$  noise of typically 1.5 volts is also provided by internal latching circuitry.

Once fired, the outputs are independent of further transitions on the inputs and are a function only of the timing components. Input pulses may be of any duration relative to the output pulse. Output pulse lengths may be varied from 40 nanoseconds to 40 seconds by choosing appropriate timing components. With no external timing components (i.e., pin ⑨ connected to pin ⑭, pins ⑩, ⑪ open) an output pulse of typically 30 nanoseconds is achieved which may be used as a dc triggered reset signal. Output rise and fall times are TTL compatible and independent of pulse length.

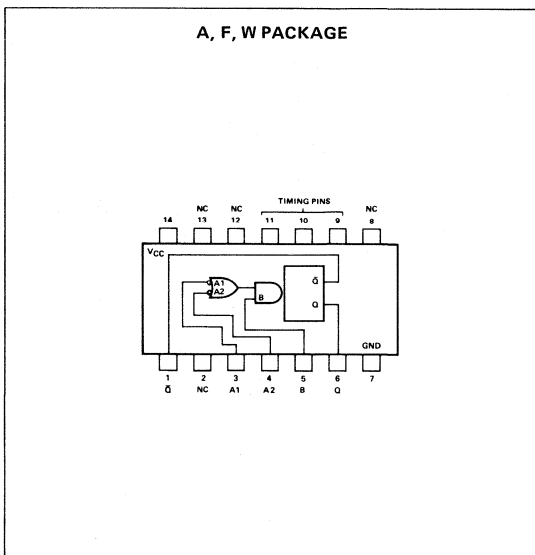
Pulse width is achieved through internal compensation and is virtually independent of  $V_{CC}$  and temperature. In most applications, pulse stability will only be limited by the accuracy of external timing components.

Jitter-free operation is maintained over the full temperature and  $V_{CC}$  range for more than six decades of timing capacitance (10 pF to 10 $\mu$ F) and more than one decade of timing resistance (2k $\Omega$  to 40k $\Omega$ ). Throughout these ranges, pulse width is defined by the relationship  $t_{p(out)} = C_T R_T \log_e 2$ .

Circuit performance is achieved with a nominal power dissipation of 90 milliwatts at 5 volts (50% duty cycle) and a quiescent dissipation of typically 65 milliwatts.

Duty cycles as high as 90% are achieved when using  $R_T = 40k\Omega$ . Higher duty cycles are achievable if a certain amount of pulse-width jitter is allowed.

#### PIN CONFIGURATIONS



#### TRUTH TABLE

$t_n$ INPUT			$t_{n+1}$ INPUT			OUTPUT
A1	A2	B	A1	A2	B	
1	1	0	1	1	1	Inhibit
0	X	1	0	X	0	Inhibit
X	0	1	X	0	0	Inhibit
0	X	0	0	X	1	One Shot
X	0	0	X	0	1	One Shot
1	1	1	X	0	1	One Shot
1	1	1	0	X	1	One Shot
X	0	0	X	1	0	Inhibit
0	X	0	1	X	0	Inhibit
X	0	1	1	1	1	Inhibit
0	X	1	1	1	1	Inhibit
1	1	0	X	0	0	Inhibit
1	1	0	0	X	0	Inhibit

- A1 and A2 are negative-edge-triggered logic inputs, and will trigger the one shot when either or both go to logical 0 with B at logical 1.
- B is a positive Schmitt-trigger input for slow edges or level detection, and will trigger the one shot when B goes to logical 1 with either A1 or A2 at logical 0. (See Truth Table)
- External timing capacitor may be connected between pin ⑩ (positive) and pin ⑪. With no external capacitance, an output pulse width of 30ns is obtained typically.
- To use the internal timing resistor (2k $\Omega$  nominal), connect pin ⑨ to pin ⑭.
- To obtain variable pulse width connect external variable resistance between pin ⑨ and pin ⑭. No external current limiting is needed.
- For accurate repeatable pulse widths connect an external resistor between pin ⑪ and pin ⑭ with pin ⑨ open-circuit.
- $t_n$  = time before input transition.
- $t_{n+1}$  = time after input transition.
- x indicates that either a logical 0 or 1, may be present.

$$1 = V_{in(1)} \geq 2V$$

$$0 = V_{in(0)} \leq 0.8V$$

# SIGNETICS MONOSTABLE MULTIVIBRATOR ■ N74121, S54121

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :				V
N74121 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Input Pulse Rise/Fall Time: Schmitt Input (B)			1	V/s
Logic Inputs (A1, A2)			1	V/ $\mu$ s
Input Pulse Width	50			ns
External Timing Resistance Between Pins (11) and (14) (Pin (9) open)	1.4			k $\Omega$
External Timing Resistance: S54121			30	k $\Omega$
N74121			40	k $\Omega$
Timing Capacitance	0		1000	$\mu$ F
Output Pulse Width			40	s
Duty Cycle: $R_T = 2k\Omega$			67%	
$R_T = 30k\Omega$ (S54121) or			90%	
$R_T = 40k\Omega$ (N74121)				

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT	
$V_{T+}$	Positive-going threshold voltage at A input $V_{CC} = \text{MIN}$		1.4	2	V	
$V_{T-}$	Negative-going threshold voltage at A input $V_{CC} = \text{MIN}$	0.8	1.4		V	
$V_{T+}$	Positive-going threshold voltage at B input $V_{CC} = \text{MIN}$		1.55	2	V	
$V_{T-}$	Negative-going threshold voltage at B input $V_{CC} = \text{MIN}$	0.8	1.35		V	
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 16\text{mA}$		0.22	0.4	V	
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}$ , $I_{\text{load}} = -400\mu\text{A}$	2.4	3.3		V	
$I_{in(0)}$	Logical 0 level input current at A <sub>1</sub> of A <sub>2</sub> $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-1	-1.6	mA	
$I_{in(0)}$	Logical 0 level input current at B $V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	-3.2	mA	
$I_{in(1)}$	Logical 1 level input current at A <sub>1</sub> of A <sub>2</sub> $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$		2	40	$\mu$ A	
$I_{in(1)}$	Logical 1 level input current at A <sub>1</sub> of A <sub>2</sub> $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$		0.05	1	mA	
$I_{in(1)}$	Logical 1 level input current at B $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$		4	80	$\mu$ A	
$I_{in(1)}$	Logical 1 level input current at B $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$		0.05	1	mA	
$I_{OS}$	Short circuit output current at Q or $\bar{Q}$ <sup>†</sup> $V_{CC} = \text{MAX}$	S54121 N74121	-20 -18	-25 -25	-55 -55	mA
$I_{CC}$	Power supply current in quiescent (unfired) state $V_{CC} = \text{MAX}$		13	25	mA	
$I_{CC}$	Power supply current in fired state $V_{CC} = \text{MAX}$		23	40	mA	

# SIGNETICS MONOSTABLE MULTIVIBRATOR ■ N74121, S54121

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

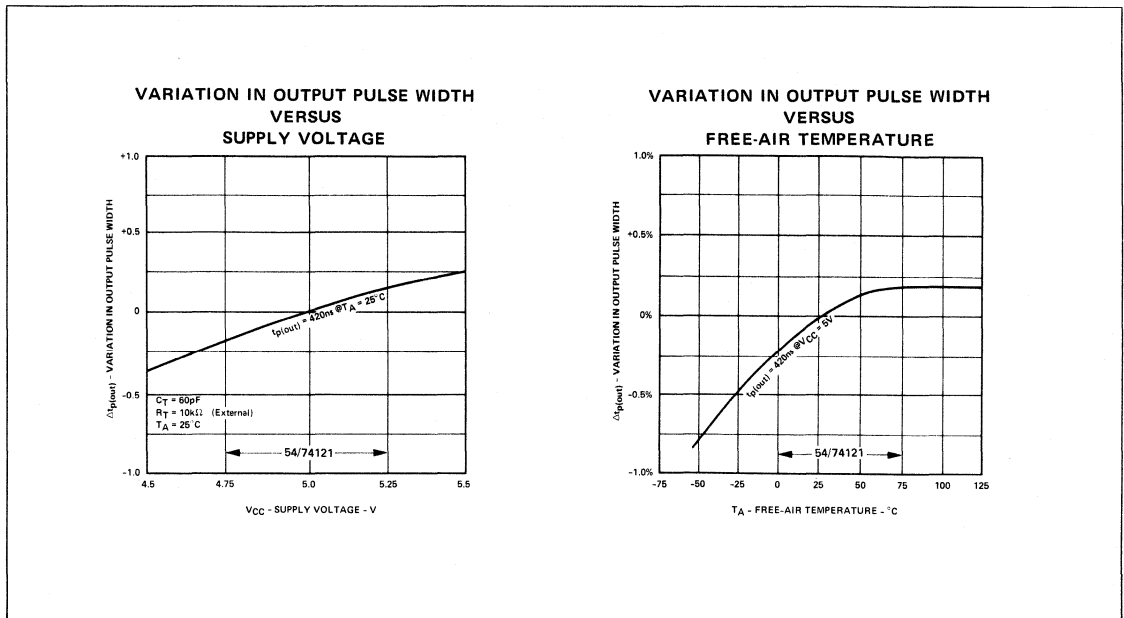
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd1}$ Propagation delay time to logical 1 level from B input to Q output	$C_L = 15pF$ , $C_T = 80pF$	15	35	55	ns
$t_{pd1}$ Propagation delay time to logical 1 level from A1/A2 inputs to Q output	$C_L = 15pF$ , $C_T = 80pF$	25	45	70	ns
$t_{pd0}$ Propagation delay time to logical 0 level from B input to $\bar{Q}$ output	$C_L = 15pF$ , $C_T = 80pF$	20	40	65	ns
$t_{pd0}$ Propagation delay time to logical 0 level from A1/A2 inputs to $\bar{Q}$ output	$C_L = 15pF$ , $C_T = 80pF$	30	50	80	ns
$t_{p(out)}$ Pulse width obtained using internal timing resistor	$C_L = 15pF$ , $R_T = \text{Open}$ , Pin (9) to $V_{CC}$	70	110	150	ns
$t_{p(out)}$ Pulse width obtained with zero timing capacitance	$C_L = 15pF$ , $R_T = \text{Open}$ , Pin (9) to $V_{CC}$	20	30	50	ns
$t_{p(out)}$ Pulse width obtained using external timing resistor	$C_L = 15pF$ , $R_T = 10k\Omega$ , Pin (9) Open	600	700	800	ns
$t_{p(out)}$ Pulse width obtained using external timing resistor	$C_L = 15pF$ , $R_T = 10k\Omega$ , Pin (9) Open	6	7	8	ms
$t_{hold}$ Minimum duration of trigger pulse	$C_L = 15pF$ , $R_T = \text{Open}$ , Pin (9) to $V_{CC}$		30	50	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

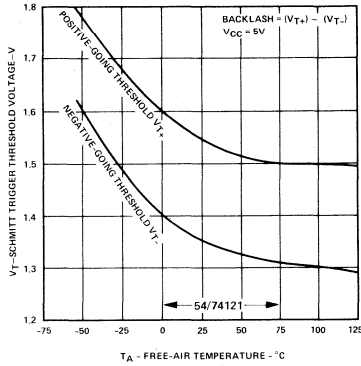
## TYPICAL CHARACTERISTICS



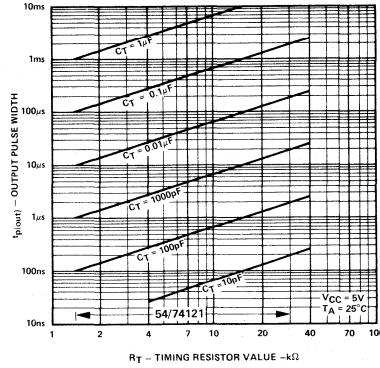
# SIGNETICS MONOSTABLE MULTIVIBRATOR ■ N74121, S54121

## TYPICAL CHARACTERISTICS (Cont'd)

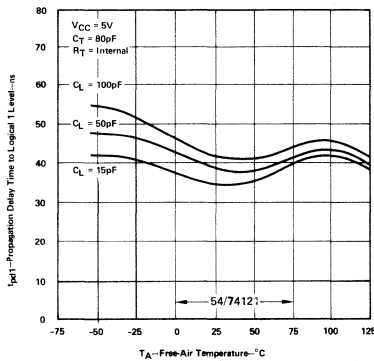
**SCHMITT TRIGGER THRESHOLD VOLTAGE  
VERSUS  
FREE-AIR TEMPERATURE**



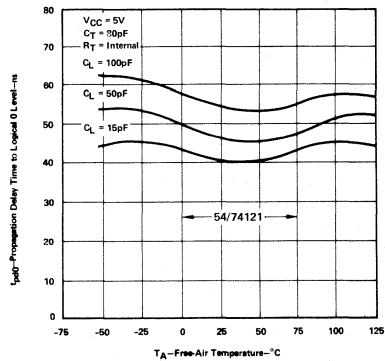
**OUTPUT PULSE WIDTH  
VERSUS  
TIMING RESISTOR VALUE**



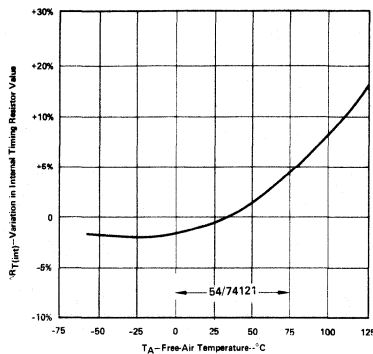
**PROPAGATION DELAY TIME TO LOGICAL 1 LEVEL (B INPUT TO Q OUTPUT)  
VERSUS  
FREE-AIR TEMPERATURE**



**PROPAGATION DELAY TIME TO LOGICAL 0 LEVEL (B INPUT TO Q OUTPUT)  
VERSUS  
FREE-AIR TEMPERATURE**



**VARIATION IN INTERNAL TIMING RESISTOR VALUE  
VERSUS  
FREE-AIR TEMPERATURE**



N74122-A,F • S54123-B,F,W • N74123-B,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These monostables are designed to provide the system designer with complete flexibility in controlling the pulse width, either to lengthen the pulse by retriggering, or to shorten by clearing. N74122 has an internal timing resistor which allows the circuit to be operated with only an external capacitor, if so desired. Applications requiring more precise pulse widths and not requiring the clear feature can best be satisfied with N74121.

The output pulse is primarily a function of the external capacitor and resistor. For  $C_{ext} > 1000pF$ , the output pulse width ( $t_w$ ) is defined as:

$$t_w = 0.32 R_T C_{ext} \left( 1 + \frac{0.7}{R_T} \right)$$

where

$R_T$  is in  $k\Omega$  (either internal or external timing resistor)

$C_{ext}$  is in  $pF$

$t_w$  is in  $ns$

For pulse widths when  $C_{ext} \leq 1000pF$ , see Figure B.

These circuits are fully compatible with most TTL or DTL families. Inputs are diode-clamped to minimize reflections due to transmission-line effects, which simplifies design. Typical power dissipation per one shot is 115 milliwatts; typical average propagation delay time to the Q output is 21 nanoseconds. The N74122 and N74123 are characterized for operation from  $0^\circ C$  to  $70^\circ C$ .

### TRUTH TABLE (See Note A)

N74122					
INPUTS				OUTPUTS	
A <sub>1</sub>	A <sub>2</sub>	B <sub>1</sub>	B <sub>2</sub>	Q	$\bar{Q}$
H	H	X	X	L	H
X	X	L	X	L	H
X	X	X	L	L	H
L	X	H	H	L	H
L	X	↑	H	┐	┐
L	X	H	↑	┐	┐
X	L	H	H	L	H
X	L	↑	H	┐	┐
X	L	H	↑	┐	┐
H	↓	H	H	┐	┐
↓	↓	H	H	┐	┐
	H	H	H	┐	┐

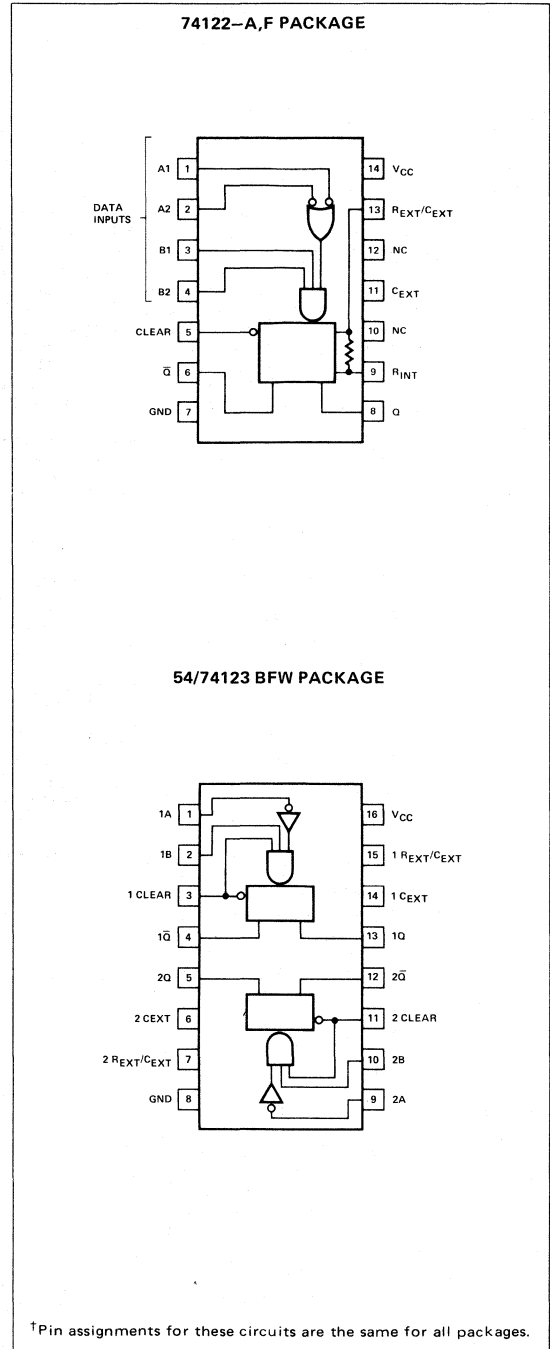
  

S54123, N74123			
INPUTS		OUTPUTS	
A	B	Q	$\bar{Q}$
H	X	L	H
X	L	L	H
L	↑	┐	┐
↓	H	┐	┐

### NOTES:

- A. H = high level (steady-state), L = low level (steady-state), ↑ = transition from low to high level, ↓ = transition from high to low level, ┐ = one high-level pulse, ┘ = one low-level pulse, X = irrelevant (any input, including transitions).
- B. NC = No internal connection.
- C. To use the internal timing resistor of N74122 (10kΩ nominal), connect  $R_{int}$  to  $V_{CC}$ .
- D. An external timing capacitor may be connected between  $C_{ext}$  and  $R_{ext}/C_{ext}$  (positive).

### PIN CONFIGURATIONS



# SIGNETICS RETRIGGERABLE MONOSTABLE MULTIVIBRATOR ■ N74122, S54123, N74123

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		S54123, N74122, N74123			UNIT
		MIN	NOM	MAX	
Supply Voltage $V_{CC}$		4.75	5	5.25	V
Normalized Fan-Out from each Output, N	High Logic Level Low-Logic Level			20 10	
Input data setup time, $t_{setup}$ (See Note 3)		40†			ns
Input data hold time, $t_{hold}$ (See Note 4)		40†			ns
Width of Clear Pulse, $t_w(\text{clear})$		40†			ns
External Timing Resistance		5		50	k $\Omega$
External Capacitance			No Restriction		
Wiring Capacitance at $R_{ext}/C_{ext}$ Terminal				50	pF
Operating Free-Air Temperature, $T_A$		0	25	70	$^{\circ}$ C

† These conditions are recommended for use at  $V_{CC} = 5V$ ,  $T_A = 25^{\circ}C$ .

- NOTES:
1. Voltage values, except intermitter voltage, are with respect to network ground terminal.
  2. This is the voltage between two emitters of a multiple-emitter transistor. For the N74122 circuit, this rating applies to each A input with respect to the other and to each B input with respect to the other.
  3. Setup time for a dynamic input is the interval immediately preceding the transition which constitutes the dynamic input, during which interval a steady-state logic level must be maintained at the input to ensure recognition of the transition.
  4. Hold time for a dynamic input is the interval immediately following the transition which constitutes the dynamic input, during which interval a steady-state logic level must be maintained at the input to ensure continued recognition of the transition.
  5. Ground  $C_{ext}$  to measure  $V_{OH}$  at Q,  $V_{OL}$  at  $\bar{Q}$ , or  $I_{OS}$  at Q.  $C_{ext}$  is open to measure  $V_{OH}$  at Q,  $V_{OL}$  at Q, or  $I_{OS}$  at  $\bar{Q}$ .
  6. Quiescent  $I_{CC}$  is measured (after clearing) with 2.4V applied to all clear and A inputs, B inputs grounded, all outputs open.  $C_{ext} = 0.02\mu F$ , and  $R_{ext} = 25k\Omega$ .  $R_{int}$  of S54122/N74122 is open.
  7.  $I_{CC}$  is measured in the triggered state with 2.4V applied to all clear and B inputs, A inputs grounded, all outputs open.  $C_{ext} = 0.02\mu F$ , and  $R_{ext} = 25k\Omega$ .  $R_{int}$  of S54122/N74122 is open.

## ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input clamp voltage					-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}$ , $V_{CC} = \text{MIN}$ , See Note 5	$I_I = -12\text{mA}$ $I_{OH} = -800\mu A$	2.4			V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}$ , See Note 5	$I_{OL} = 16\text{mA}$		0.22	0.4	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}$ ,	$V_I = 5.5V$			1	mA
$I_{IH}$	High-level input current	data inputs clear input $V_{CC} = \text{MAX}$ ,	$V_I = 2.4V$			40 80	$\mu A$
$I_{IL}$	Low-level input current	data inputs clear input $V_{CC} = \text{MAX}$ ,	$V_I = 0.4V$			-1.6 -3.2	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ ,	See Note 5 N74122 N74123	-10		-40	mA
$I_{CC}$	Supply current (quiescent or triggered)	See Notes 6 and 7			23 46	28 66	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^{\circ}C$ , $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level Q output, from either A input				22	33	ns
$t_{PLH}$	Propagation delay time, low-to-high-level Q output, from either B input				19	28	ns
$t_{PHL}$	Propagation delay time, high-to-low-level $\bar{Q}$ output, from either A input	$C_{ext} = 0$ , $C_L = 15\text{pF}$ ,	$R_{ext} = 5k\Omega$ , $R_L = 400\Omega$ ,		30	40	ns
$t_{PHL}$	Propagation delay time, high-to-low-level $\bar{Q}$ output, from either B input				27	36	ns
$t_{PHL}$	Propagation delay time, high-to-low-level Q output, from clear input				18	27	ns
$t_{PLH}$	Propagation delay time, low-to-high-level $\bar{Q}$ output, from clear input				30	40	ns
$t_w(\text{min})$	Minimum width of Q output pulse				45	65	ns
$t_w$	Width of Q output pulse	$C_{ext} = 1000\text{pF}$ , $C_L = 15\text{pF}$ ,	$R_{ext} = 10k\Omega$ $R_L = 400\Omega$	3.08	3.42	3.76	$\mu s$

# SIGNETICS RETRIGGERABLE MONOSTABLE MULTIVIBRATOR ■ N74122, S54123, N74123

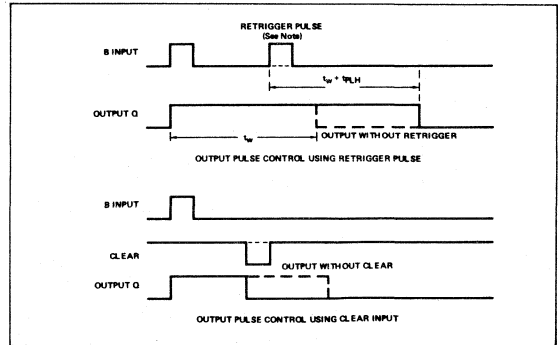
- \* For conditions shown as MIN or MAX, use the value specified under recommended operating conditions for the applicable device type.
- \*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .
- † Not more than one output should be shorted at a time.

## DESCRIPTION

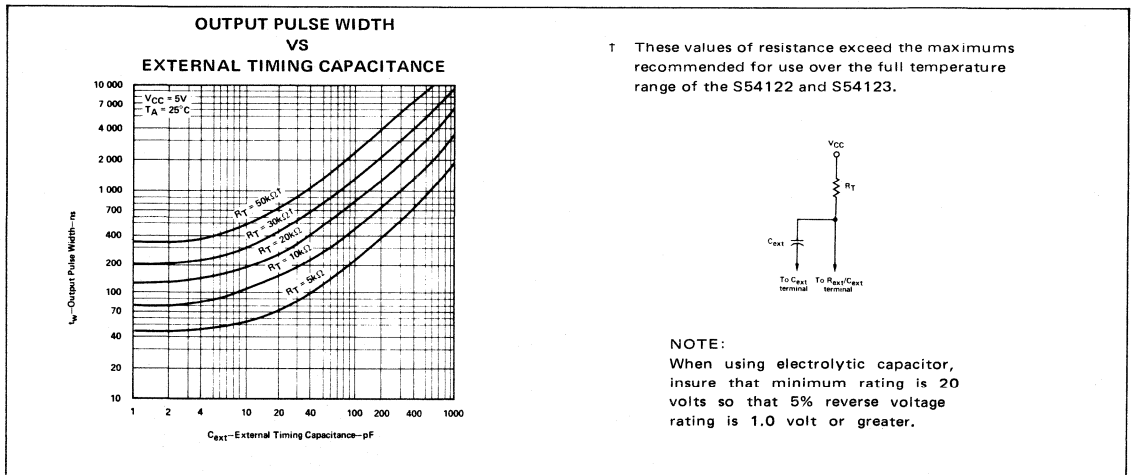
These monolithic TTL retriggerable monostable multivibrators feature dc triggering from gated low-level-active (A) and high-level-active (B) inputs, and also provide overriding direct clear inputs. Complementary outputs are provided. A full fan-out to 10 normalized Series 54/74 loads is available from each of the outputs at the low logic level, and in the high-level state, a fan-out of 20 is available. The retrigger capability simplifies the generation of output pulses of extremely long duration. By triggering the input before the output pulse is terminated, the output pulse may be extended. The overriding clear capability permits any output pulse to be terminated at a predetermined time independently of the timing components R and C.

Figure A illustrates triggering the one-shot with the high-level-active (B) inputs.

## TYPICAL INPUT/OUTPUT PULSES (Figure A)



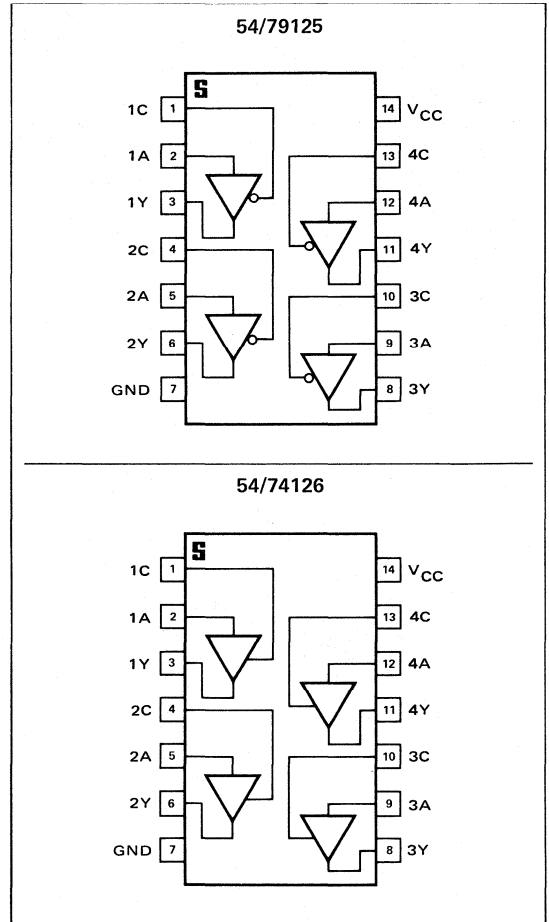
## TYPICAL CHARACTERISTICS (Figure B)



### DESCRIPTION

These bus buffer gates feature three-stage outputs which, when enabled, have the low-impedance characteristics of a TTL output with additional drive capability at high logic levels to permit driving heavily loaded bus lines without external pull-up resistors. When disabled, both output transistors are turned off presenting a high-impedance state to the bus so the output will act neither as a significant load nor as a driver. To minimize the possibility that two outputs will attempt to take a common bus to opposite logic levels, the output control circuitry is designed so that the output disable times are shorter than the output enable times.

### PIN CONFIGURATION



### ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

Supply voltage, $V_{CC}$ (see Note 1)	7V
Input voltage	5.5V
Output voltage (see Note 2)	5.5V
Operating free-air temperature range:	
54125, 54126 Circuits	-55°C to 125°C
74125, 74126 Circuits	0°C to 70°C
Storage temperature range	-65°C to 150°C

- NOTES
1. Voltage values are with respect to network ground terminal.
  2. This is the maximum voltage which should be applied to any output when it is in the off state.

### RECOMMENDED OPERATING CONDITIONS

	54125, 54126			74125, 74126			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from any output, N	High logic level			130			
	Low logic level			10			
High-level output current, $I_{OH}$	-2			-5.2			mA
Operating free-air temperature, $T_A$	-55			0			70 °C



**SIGNETICS QUAD BUS BUFFER GATES WITH TRI-STATE OUTPUTS ■ S54/N74125, S54/N74126**

**ELECTRICAL CHARACTERISTICS** over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
V <sub>IH</sub>	High-level input voltage		2			V
V <sub>IL</sub>	Low-level input voltage				0.8	V
V <sub>I</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12 mA			-1.5	V
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = MAX	2.4			V
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 16 mA			0.4	V
I <sub>O(off)</sub>	Off-state (high-impedance state) output current	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V	V <sub>O</sub> = 2.4 V		40	μA
			V <sub>O</sub> = 0.4 V		-40	
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V			1	mA
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4 V			40	μA
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V			-1.6	mA
I <sub>OS</sub>	Short-circuit output current‡	V <sub>CC</sub> = MAX	54125, 54126	-30	-70	mA
			74125, 74126	-28	-70	
I <sub>CC</sub>	Supply current	V <sub>CC</sub> = MAX, See Note 3	54125, 74125	32	54	mA
			54126, 74126	36	62	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type

‡ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

§ Not more than one output should be shorted at a time.

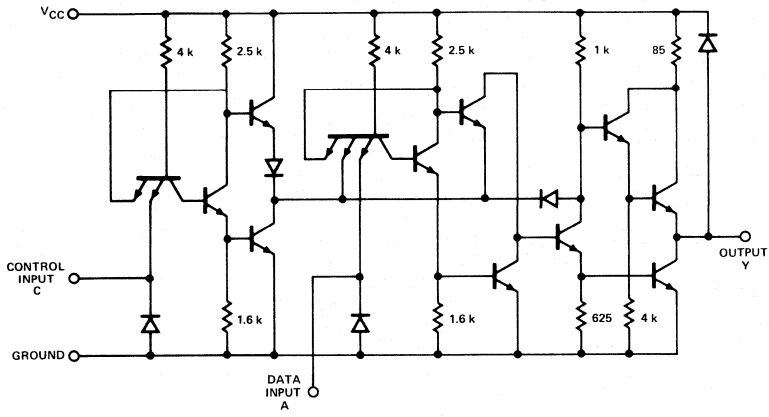
NOTE 3: I<sub>CC</sub> is measured with data inputs grounded and outputs disabled and open.

**SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C**

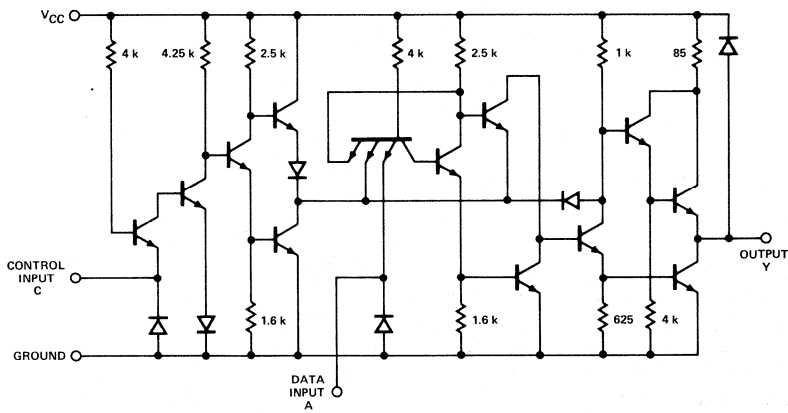
PARAMETER	TEST CONDITIONS	54125, 74125		54126, 74126		UNIT	
		MIN	TYP	MAX	MIN		TYP
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 400 Ω, See Note 4	8	13	8	13	ns
t <sub>PHL</sub>	Propagation delay time, high-to-low-level output		12	18	12	18	
t <sub>ZH</sub>	Output enable time to high level	See Note 4	11	17	11	18	ns
t <sub>ZL</sub>	Output enable time to low level		16	25	16	25	
t <sub>HZ</sub>	Output disable time from high level	C <sub>L</sub> = 5 pF, See Note 4	5	8	10	16	ns
t <sub>LZ</sub>	Output disable time from low level		7	12	12	18	

SCHEMATIC (each gate)

54125, 74125



54126, 74126



#### DESCRIPTION

Functionally these Schmitt triggers are practically identical to the 5413/7413 circuits. The 5414/7414 consists of six Schmitt-trigger inverters and the 54132/74132 consists of four 2-input NAND Schmitt triggers in single 14-pin packages. Because of the Schmitt-trigger action, the gate has widely separated positive-going and negative-going threshold levels. Hysteresis, the difference between the two threshold levels, is typically 830 millivolts which means that these devices can be used effectively as an interface even with marginal digital signals.

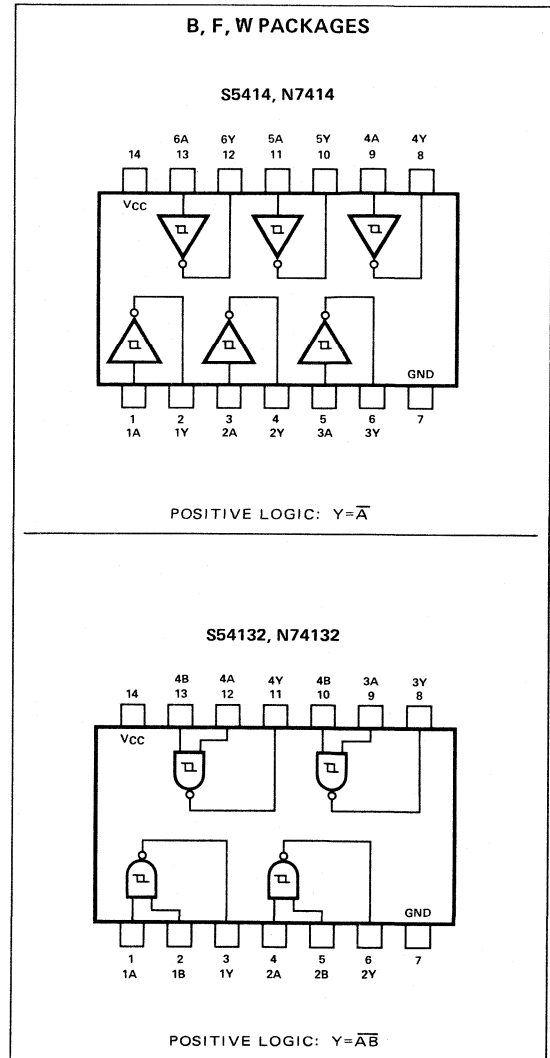
As with the 5413 and 7413, an important design feature is the built-in temperature compensation which ensures very high stability of the threshold levels and the hysteresis over a very wide temperature range. Typically, the hysteresis changes by three percent over the temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ , and the upper threshold changes by one percent over the same range. Although standard TTL gates are designed to respond to dc threshold levels and their inputs are diode-clamped to suppress high-frequency ringing, they are commonly susceptible to false triggering from ac ripple on slow-rising and slow-falling transitions. The widely separated thresholds of these Schmitt-trigger circuits are less susceptible to false triggering and the circuits can be triggered from the slowest of input ramps and still produce clean, jitter-free output signals.

These circuits are fully compatible with most DTL and other TTL including Schottky and MSI circuits. The 5414 and 54132 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 7414 and 74132 are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### ABSOLUTE MAXIMUM RATINGS OVER OPERATING FREE-AIR TEMPERATURE RANGE (Unless otherwise noted)

Supply Voltage, $V_{CC}$ (See Note 1)	7 V
Input Voltage	5.5 V
Interemitter Voltage: 54132, 74132 Circuits only (See Note 2)	5.5 V
Operating Free-Air Temperature Range:	
5414, 54132 Circuits	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
7414, 74132 Circuits	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

#### PIN CONFIGURATIONS



#### NOTES:

1. Voltage values, except interemitter voltage, are with respect to the network ground terminal.
2. This is the voltage between two emitters of a multiple-emitter transistor. For 54132/74132 circuits, this rating applies between the two inputs of any gate.

RECOMMENDED OPERATING CONDITIONS

PARAMETER		5414, 54132			7414, 74132			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, $N$	High logic level			20			20	
	Low logic level			10			10	
Operating free-air temperature, $T_A$		-55		125	0		70	°C

ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range (unless otherwise noted)

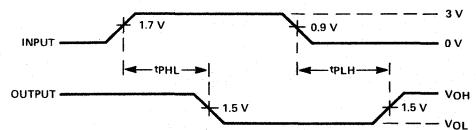
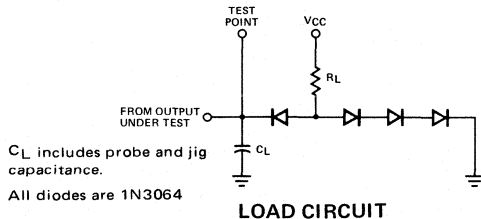
PARAMETER	TEST CONDITIONS <sup>1</sup>	MIN	TYP <sup>2</sup>	MAX	UNIT
$V_{T+}$ Positive threshold voltage	$V_{CC} = 5V$	1.5	1.7	2	V
$V_{T-}$ Negative-going threshold voltage	$V_{CC} = 5V$	0.6	0.9	1.1	V
$V_{T+} - V_{T-}$ Hysteresis	$V_{CC} = 5V$	0.4	0.8		V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_I = 0.6V,$ $I_{OH} = -800\mu A$	2.4	3.3		V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_I = 2V,$ $I_{OL} = 16\text{mA}$		0.22	0.4	V
$I_{T+}$ Input current at positive-going threshold	$V_{CC} = 5V, V_I = V_{T+}$		-0.43		mA
$I_{T-}$ Input current at negative-going threshold	$V_{CC} = 5V, V_I = V_{T-}$		-0.56		mA
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5V$			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4V$			40	$\mu A$
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4V$		-0.8	-1.2	mA
$I_{OS}$ Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX}$	-18		-55	mA
$I_{CCH}$ Supply current, high-level output (average per gate or inverter)	$V_{CC} = \text{MAX}, V_I = 0$		3.7	6	mA
$I_{CCL}$ Supply current, low-level output (average per gate or inverter)	$V_{CC} = \text{MAX}, V_I = 4.5V$		6.5	10	mA

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.
2. All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .
3. Not more than one output should be shorted at a time.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$ Propagation delay time, low-to-high-level output	$C_L = 15\text{pF}, R_L = 400 \Omega$ See Figure 1		15	22	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output			15	22	

PARAMETER MEASUREMENT INFORMATION



N74141-B

DIGITAL 54/74 TTL SERIES

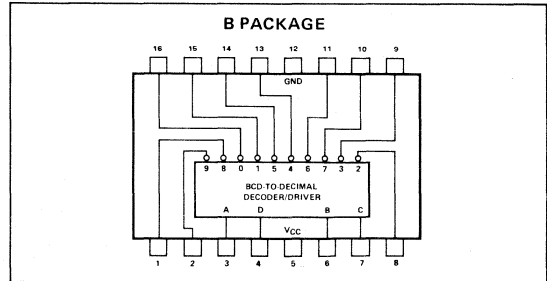
### DESCRIPTION

The N74141 is a BCD-to-decimal decoder designed specifically to drive cold-cathode indicator tubes. This decoder demonstrates an improved capability to minimize switching transients in order to maintain a stable display.

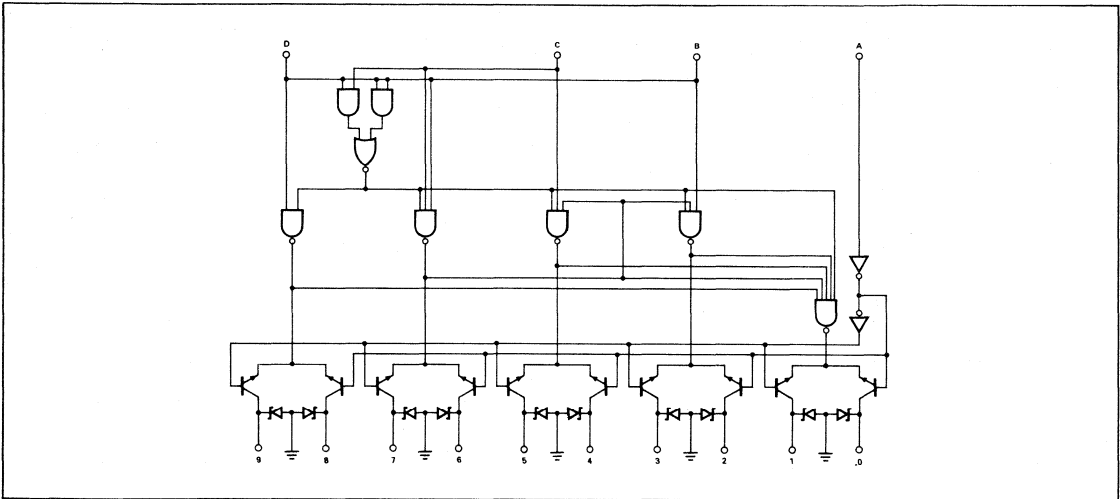
Full decoding is provided for all possible input states. For binary inputs 10 through 15, all the outputs are off. Therefore the N74141, combined with a minimum of external circuitry, can use these invalid codes in blanking leading- and/or trailing-edge zeros in a display as shown in the typical application data. The then high-performance, n-p-n output transistors have a maximum reverse current of 50 microamperes at 55 volts.

Low-forward-impedance diodes are also provided for each input to clamp negative-voltage transients in order to minimize transmission-line effects. Power dissipation is typically 55 milliwatts, which is about one-half the power requirement of earlier designs. The N74141 is characterized for operation over the temperature range of 0°C to 70°C.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



### TRUTH TABLE

INPUT				OUTPUT ON*
D	C	B	A	
L	L	L	L	0
L	L	L	H	1
L	L	H	L	2
L	L	H	H	3
L	H	L	L	4
L	H	L	H	5
L	H	H	L	6
L	H	H	H	7
H	L	L	L	8
H	L	L	H	9
H	L	H	L	NONE
H	L	H	H	NONE
H	H	L	L	NONE
H	H	L	H	NONE
H	H	H	L	NONE
H	H	H	H	NONE

H = high level, L = low level

\*All other outputs are off

# SIGNETICS BCD-TO-DECIMAL DECODER/DRIVER WITH BLANKING ■ N74141

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ (See Note 1)	4.75	5	5.25	V
Output Voltage (See Notes 1 and 2)			65	V
Operating Free-Air Temperature Range	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$V_{O(on)}$	On-state output voltage			2.5	V
$V_{O(off)}$	Off-state output voltage for input counts 0 thru 9		65		V
$I_{O(off)}$	Off-state reverse current			50	μA
$I_{O(off)}$	Off-state reverse current for input counts 10 thru 15			5	μA
$I_{IH}$	High-level input current			40	μA
$I_{IL}$	Low-level input current into A			1	mA
$I_{IL}$	Low-level input current into B, C, or D			-1.6	mA
$I_{CC}$	Supply current		11	16	mA

- \* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions  
 \*\* This typical value is at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

### DESCRIPTION

These TTL encoders feature priority decoding of the inputs to ensure that only the highest-order data line is encoded. The 54147 and 74147 encode nine data lines to four-line (8-4-2-1) BCD. The implied decimal zero condition requires no input condition as zero is encoded when all nine data lines are at a high logic level. All inputs are buffered to represent one normalized Series 54/74 load. The 54148 and 74148 encode eight data lines to three-line (4-2-1) binary (octal). Cascading circuitry (enable input EI and enable output EO) has been provided to allow octal expansion without the need for external circuitry. For all types, data inputs and outputs are active at the low logic level.

FUNCTION TABLE 54147, 74147

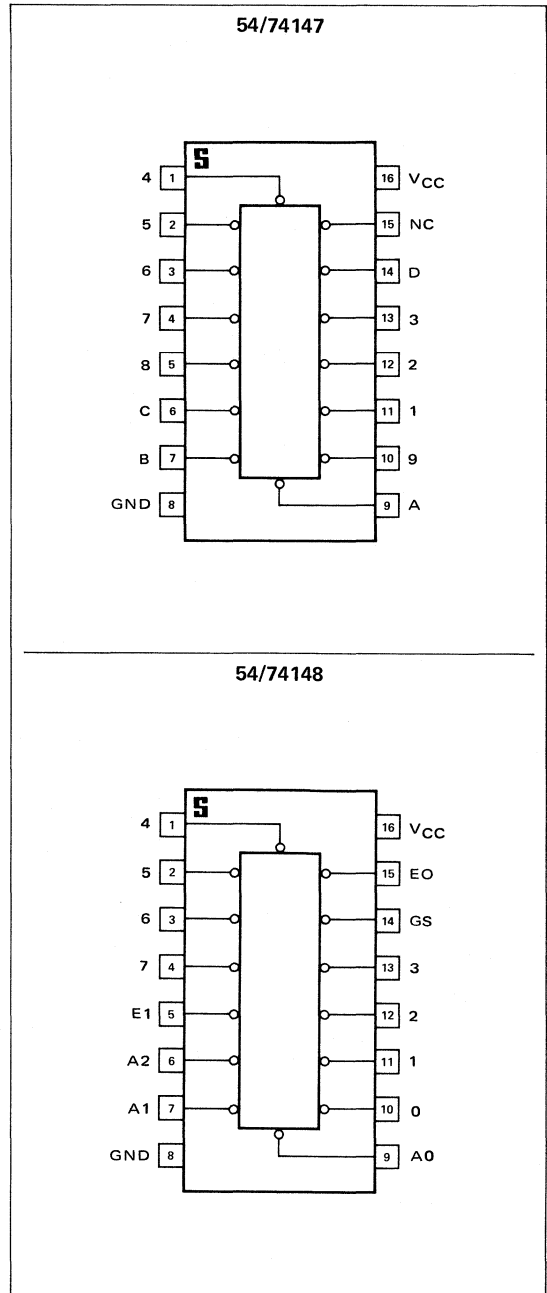
INPUTS									OUTPUTS			
1	2	3	4	5	6	7	8	9	D	C	B	A
H	H	H	H	H	H	H	H	H	H	H	H	H
X	X	X	X	X	X	X	X	L	L	H	H	L
X	X	X	X	X	X	X	L	H	L	H	H	H
X	X	X	X	X	X	L	H	H	H	L	L	L
X	X	X	X	X	L	H	H	H	H	L	L	H
X	X	X	X	L	H	H	H	H	H	L	H	L
X	X	L	H	H	H	H	H	H	H	H	L	L
X	L	H	H	H	H	H	H	H	H	H	L	H
L	H	H	H	H	H	H	H	H	H	H	H	L

H = high logic level, L = low logic level, X = irrelevant

FUNCTION TABLE 54148, 74148

INPUTS								OUTPUTS					
EI	0	1	2	3	4	5	6	7	A2	A1	A0	GS	EO
H	X	X	X	X	X	X	X	X	H	H	H	H	H
L	H	H	H	H	H	H	H	H	H	H	H	H	L
L	X	X	X	X	X	X	X	L	L	L	L	L	H
L	X	X	X	X	X	L	H	H	L	L	H	L	H
L	X	X	X	X	L	H	H	H	L	H	H	L	H
L	X	X	L	H	H	H	H	H	H	L	H	L	H
L	X	L	H	H	H	H	H	H	H	H	L	L	H
L	L	H	H	H	H	H	H	H	H	H	H	L	H

### PIN CONFIGURATION



RECOMMENDED OPERATING CONDITIONS

		54147, 54148			74147, 74148			UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX			
Supply voltage, V <sub>CC</sub>		4.5	5	5.5	4.75	5	5.25	V		
Normalized fan-out from any output, N	High logic level				20					
	Low logic level				10					
Operating free-air temperature, T <sub>A</sub>		-55			125			0	70	°C

ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS*	54147, 74147		54148, 74148		UNIT	
			MIN	TYP†	MAX	MIN		TYP†
V <sub>IH</sub>	High-level input voltage		2		2		V	
V <sub>IL</sub>	Low-level input voltage				0.8		V	
V <sub>I</sub>	Input clamp voltage	V <sub>CC</sub> = MAX, I <sub>I</sub> = -12mA			-1.5		V	
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OH</sub> = -800µA	2.4	3.3	2.4	3.3	V	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OL</sub> = 16mA			0.4		V	
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1		1	mA
I <sub>IH</sub>	High-level input current	0 input			40		40	µA
		Any input except 0			80		80	
I <sub>IL</sub>	Low-level input current	0 input			-1.6		-1.6	mA
		Any input except 0			-3.2		-3.2	
I <sub>OS</sub>	Short-circuit output current‡	V <sub>CC</sub> = MAX	-35	-85	-35	-85	mA	
I <sub>CC</sub>	Supply current	V <sub>CC</sub> = MAX, See Note 3	50	70	40	60	60	mA
		Condition 1 Condition 2	42	62	35	55	55	mA

NOTE 3: For 54147, 74147, I<sub>CC</sub> (condition 1) is measured with input 7 grounded, other inputs and outputs open; I<sub>CC</sub> (condition 2) is measured with all inputs and outputs open. For 54148, 74148, I<sub>CC</sub> (condition 1) is measured with inputs 7 and E1 grounded, other inputs and outputs open; I<sub>CC</sub> (condition 2) is measured with all inputs and outputs open.

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

†All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.

‡Not more than one output should be shorted at a time.

54148, 74148 SWITCHING CHARACTERISTICS V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C, N = 10

PARAMETER†	FROM (INPUT)	TO (OUTPUT)	WAVEFORM	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	0 thru 7	A0,A1, or A2	In-phase output	C <sub>L</sub> = 15pF, R <sub>L</sub> = 400Ω	10	15	15	ns
			Out-of-phase output		9	14	14	
t <sub>PLH</sub> t <sub>PHL</sub>	0 thru 7	A0,A1, or A2	Out-of-phase output		13	19	19	ns
			In-phase output		10	15	15	
t <sub>PLH</sub> t <sub>PHL</sub>	0 thru 7	E0	Out-of-phase output		6	10	10	ns
			In-phase output		9	14	14	
t <sub>PLH</sub> t <sub>PHL</sub>	0 thru 7	GS	In-phase output		14	21	21	ns
			Out-of-phase output		12	18	18	
t <sub>PLH</sub> t <sub>PHL</sub>	E1	A0,A1, or A2	In-phase output	10	15	15	ns	
			Out-of-phase output	10	15	15		
t <sub>PLH</sub> t <sub>PHL</sub>	E1	GS	In-phase output	8	12	12	ns	
			Out-of-phase output	10	15	15		
t <sub>PLH</sub> t <sub>PHL</sub>	E1	E0	In-phase output	8	13	13	ns	
			Out-of-phase output	13	19	19		

†t<sub>PLH</sub> ≡ propagation delay time, low-to-high-level output.

t<sub>PHL</sub> ≡ propagation delay time, high-to-low-level output.

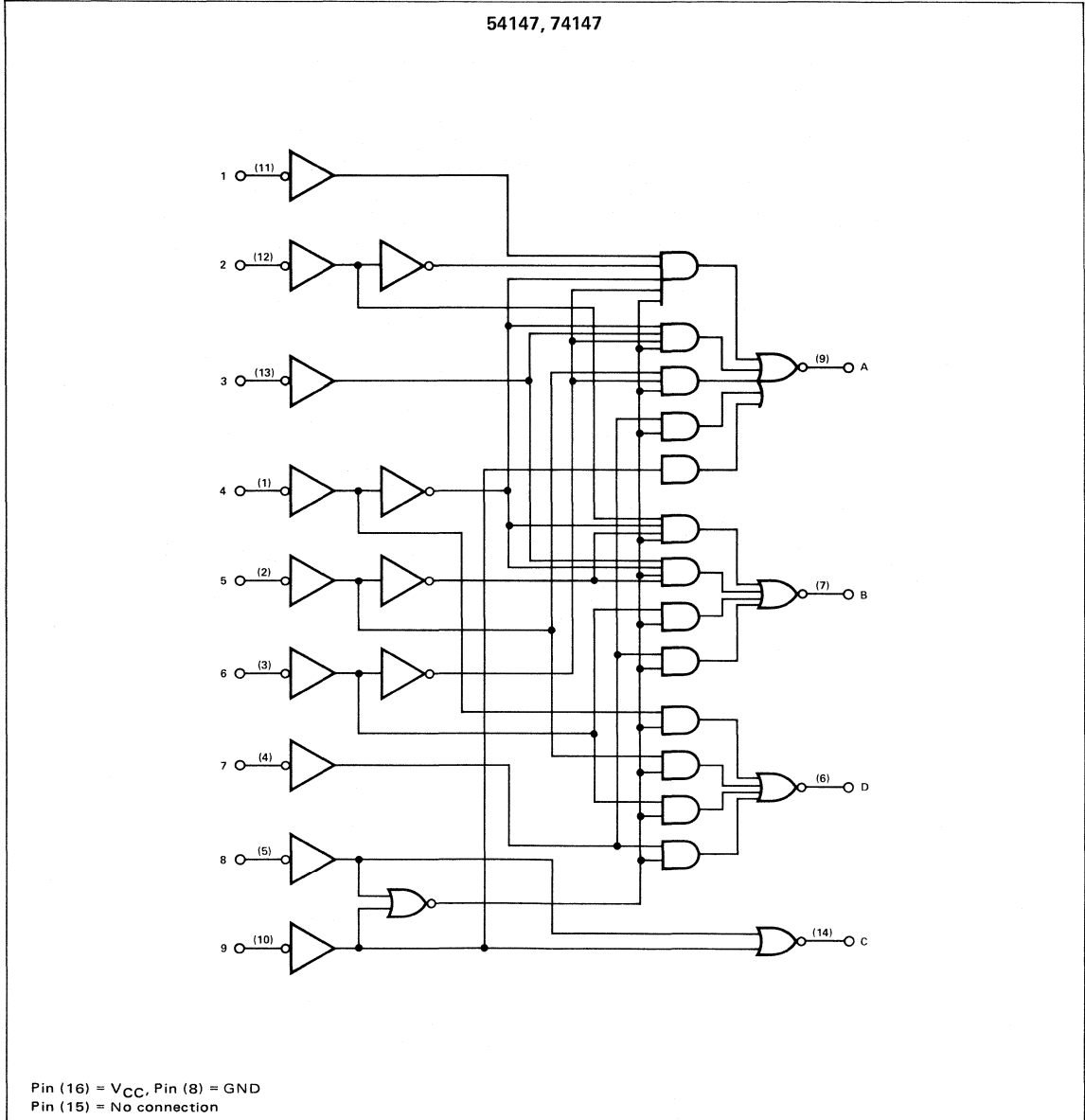


**SIGNETICS 10-LINE TO 4-LINE & 8-LINE TO 3-LINE PRIORITY ENCODERS ■ SN54/74147, SN54/74148**

54147, 74147 SWITCHING CHARACTERISTICS  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

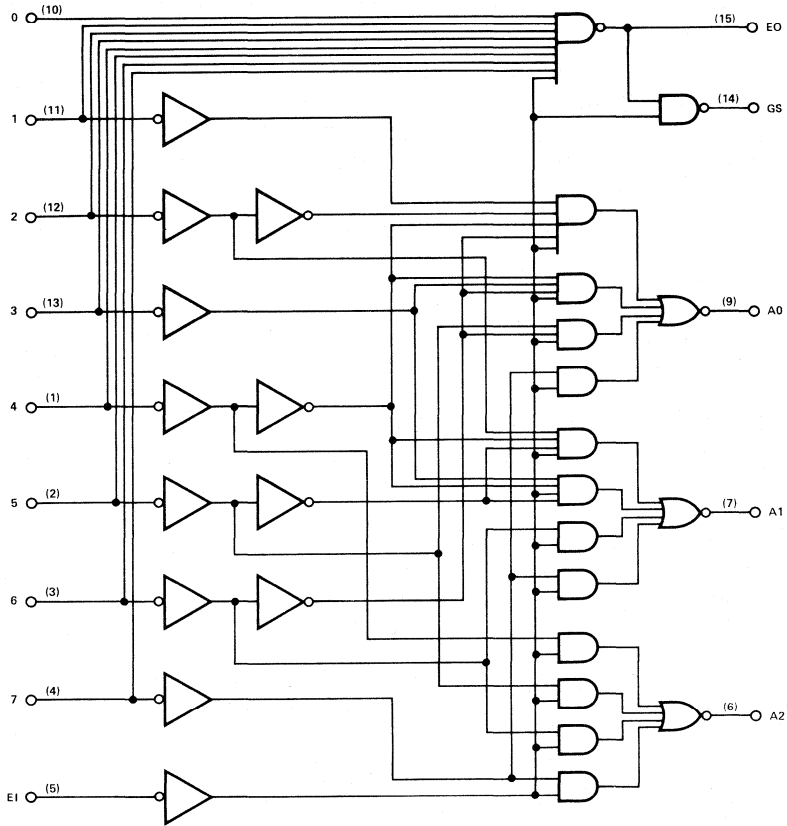
PARAMETER†	FROM (INPUT)	TO (OUTPUT)	WAVEFORM	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$ $t_{PHL}$	Any	Any	In-phase output	$C_L = 15pF$ , $R_L = 400\Omega$ See Note 4		9	14	ns
$t_{PLH}$ $t_{PHL}$	Any	Any	Out-of-phase output			13	19	
						10	15	ns

**FUNCTIONAL BLOCK DIAGRAM**



FUNCTIONAL BLOCK DIAGRAM

54148, 74148



Pin (16) = V<sub>CC</sub>, Pin (8) = GND



# SIGNETICS 16-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER ■ S54150, N74150

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54150 Circuits	4.5	5	5.5	V
N74150 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: Logical 0			10	
Logical 1			20	

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V, I_{load} = -800\mu A$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V, I_{sink} = 16mA$			0.4	V
$I_{in(1)}$ Logical 1 level input (each input)	$V_{CC} = \text{MAX}, V_{in} = 2.4V$			40	$\mu A$
	$V_{CC} = \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{in(0)}$ Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			-1.6	mA
	$V_{CC} = \text{MAX}, V_{OUT} = 0$	-20		-55	mA
$I_{OS}$ Short circuit output current†		-18		-55	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}, V_{in} = 4.5V$		40	68	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	A,B,orC(4 levels)	Y	$C_L = 15pF, R_L = 400\Omega$		20	30	ns
$t_{pd1}$	A,B,orC(4levels)	Y			35	52	ns
$t_{pd0}$	A,B,C,orD(3 levels)	W			22	33	ns
$t_{pd1}$	A,B,C,orD(3 levels)	W			23	35	ns
$t_{pd0}$	STROBE	Y			19	30	ns
$t_{pd1}$	STROBE	Y			35	52	ns
$t_{pd0}$	STROBE	W			21	30	ns
$t_{pd1}$	STROBE	W			15.5	24	ns
$t_{pd0}$	$D_0$ thru $D_7$	Y			16	24	ns
$t_{pd1}$	$D_0$ thru $D_7$	Y			19	29	ns
$t_{pd0}$	$E_0$ thru $E_{15}$	W			8.5	14	ns
$t_{pd1}$	$E_0$ thru $E_{15}$	W			13	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

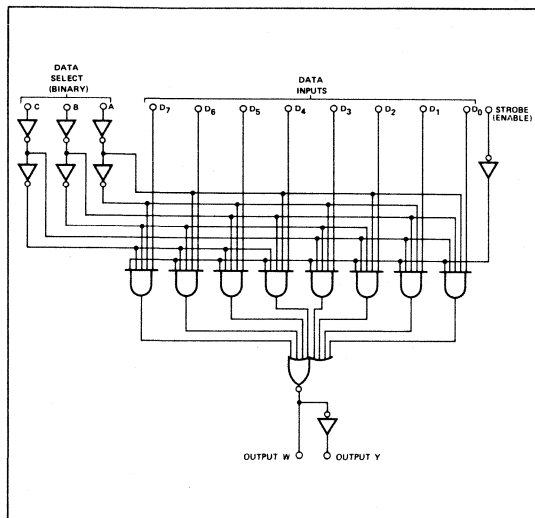
\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

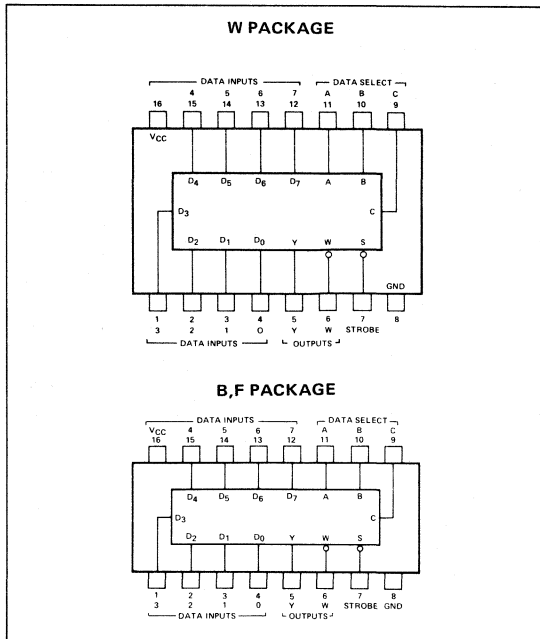
### DESCRIPTION

The 54/74151 is a one-of-eight data selector which performs parallel-to-serial data conversion. The unit incorporates an enable circuit for chip select. This allows multiplexing from N-lines to one-line. Both true and complement outputs are available.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

			INPUTS										OUTPUTS	
C	B	A	STROBE	D <sub>0</sub>	D <sub>1</sub>	D <sub>2</sub>	D <sub>3</sub>	D <sub>4</sub>	D <sub>5</sub>	D <sub>6</sub>	D <sub>7</sub>	Y	W	
X	X	X	1	X	X	X	X	X	X	X	X	0	1	
0	0	0	0	0	X	X	X	X	X	X	X	0	1	
0	0	0	0	1	X	X	X	X	X	X	X	1	0	
0	0	1	0	X	0	X	X	X	X	X	X	0	1	
0	0	1	0	X	1	X	X	X	X	X	X	1	0	
0	1	0	0	X	X	0	X	X	X	X	X	0	1	
0	1	0	0	X	X	1	X	X	X	X	X	1	0	
0	1	1	0	X	X	X	1	X	X	X	X	1	0	
1	0	0	0	X	X	X	X	0	X	X	X	0	1	
1	0	0	0	X	X	X	X	1	X	X	X	1	0	
1	0	1	0	X	X	X	X	X	0	X	X	0	1	
1	0	1	0	X	X	X	X	X	1	X	X	1	0	
1	1	0	0	X	X	X	X	X	X	0	X	0	1	
1	1	0	0	X	X	X	X	X	X	1	X	1	0	
1	1	1	0	X	X	X	X	X	X	X	0	0	1	
1	1	1	0	X	X	X	X	X	X	X	1	1	0	

When used to indicate an input, X = irrelevant.

### RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage V <sub>CC</sub> : S54151 Circuits	4.5	5	5.5	V
N74151 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: Logical 0			10	
Logical 1			20	

# SIGNETICS 8-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER ■ S54151, N74151

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $V_{in(1)} = 2V$ , $V_{in(0)} = 0.8V$ , $I_{load} = -800 \mu A$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $V_{in(1)} = 2V$ , $V_{in(0)} = 0.8V$ , $I_{sink} = 16mA$			0.4	V
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4V$			40	$\mu A$
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5V$			1	mA
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4V$			-1.6	mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$ , $V_{out} = 0$	-20		-55	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5V$		29	48	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	A,B,orC(4 levels)	Y	$C_L = 15pF$ , $R_L = 400\Omega$		20	30	ns
$t_{pd1}$	A,B,orC(4 levels)	Y			35	52	ns
$t_{pd0}$	A,B,C,orD(3 levels)	W			22	33	ns
$t_{pd1}$	A,B,C,orD(3 levels)	W			23	35	ns
$t_{pd0}$	STROBE	Y			19	30	ns
$t_{pd1}$	STROBE	Y			35	52	ns
$t_{pd0}$	STROBE	W			21	30	ns
$t_{pd1}$	STROBE	W			15.5	24	ns
$t_{pd0}$	D <sub>0</sub> thru D <sub>7</sub>	Y			16	24	ns
$t_{pd1}$	D <sub>0</sub> thru D <sub>7</sub>	Y			19	29	ns
$t_{pd0}$	E <sub>0</sub> thru E <sub>15</sub>	W			8.5	14	ns
$t_{pd1}$	E <sub>0</sub> thru E <sub>15</sub>	W			13	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

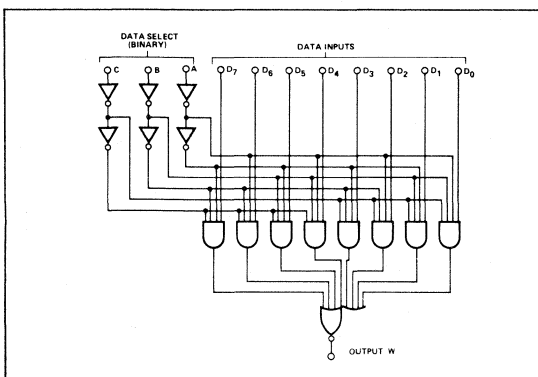
S54152-W

DIGITAL 54/74 TTL SERIES

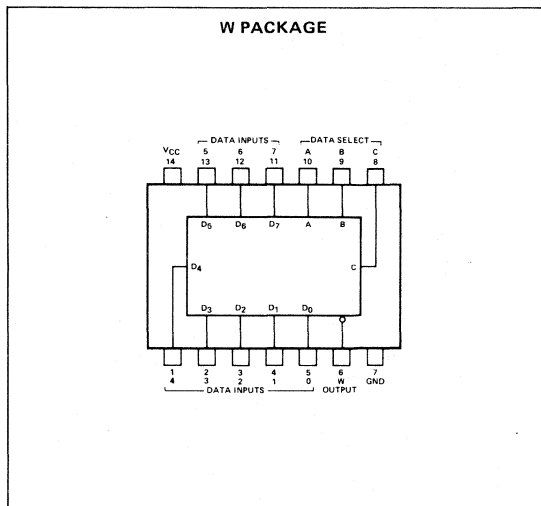
### DESCRIPTION

The S54152 is a one-of-eight data selector which performs parallel to serial data conversion. The S54152 is identical to the S54152 with the exclusion of the true output and strobe. It is available in the 14-pin flatpak only.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

INPUTS												OUTPUTS	
C	B	A	STROBE	D <sub>0</sub>	D <sub>1</sub>	D <sub>2</sub>	D <sub>3</sub>	D <sub>4</sub>	D <sub>5</sub>	D <sub>6</sub>	D <sub>7</sub>	Y(1)	W
X	X	X	1	X	X	X	X	X	X	X	X	0	1
0	0	0	0	0	X	X	X	X	X	X	X	0	1
0	0	0	0	1	X	X	X	X	X	X	X	1	0
0	0	1	0	X	0	X	X	X	X	X	X	0	1
0	0	1	0	X	1	X	X	X	X	X	X	1	0
0	1	0	0	X	X	0	X	X	X	X	X	0	1
0	1	0	0	X	X	1	X	X	X	X	X	1	0
0	1	1	0	X	X	X	0	X	X	X	X	0	1
0	1	1	0	X	X	X	1	X	X	X	X	1	0
1	0	0	0	X	X	X	X	0	X	X	X	0	1
1	0	0	0	X	X	X	X	1	X	X	X	1	0
1	0	1	0	X	X	X	X	X	0	X	X	0	1
1	0	1	0	X	X	X	X	1	X	X	X	1	0
1	1	0	0	X	X	X	X	X	X	0	X	0	1
1	1	0	0	X	X	X	X	X	X	1	X	1	0
1	1	1	0	X	X	X	X	X	X	X	0	0	1
1	1	1	0	X	X	X	X	X	X	X	1	1	0

When used to indicate an input, X = Irrelevant.

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage V <sub>CC</sub> : S54152 Circuits	4.5	5	5.5	V
N74152 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: Logical 0			10	
Logical 1			20	

# SIGNETICS 8-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER ■ S54152

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V,$ $I_{load} = -800\mu A$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V, V_{in(0)} = 0.8V,$ $I_{sink} = 16mA$			0.4	V
$I_{in(1)}$	Logical 1 level input (each input)	$V_{CC} = \text{MAX}, V_{in} = 2.4V$			40	$\mu A$
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 5.5V$			1	mA
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			-1.6	mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX},$ $V_{out} = 0$	-20		-55	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, V_{in} = 4.5V$	-18	26	-55	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	A, B, or C (4 levels)	Y	$C_L = 15pF, R_L = 400\Omega$		20	30	ns
$t_{pd1}$	A, B, or C (4 levels)	Y			35	52	ns
$t_{pd0}$	A, B, C, or D (3 levels)	W			22	33	ns
$t_{pd1}$	A, B, C, or D (3 levels)	W			23	35	ns
$t_{pd0}$	STROBE	Y			19	30	ns
$t_{pd1}$	STROBE	Y			35	52	ns
$t_{pd0}$	STROBE	W			21	30	ns
$t_{pd1}$	STROBE	W			15.5	24	ns
$t_{pd0}$	D <sub>0</sub> thru D <sub>7</sub>	Y			16	24	ns
$t_{pd1}$	D <sub>0</sub> thru D <sub>7</sub>	Y			19	29	ns
$t_{pd0}$	E <sub>0</sub> thru E <sub>15</sub>	W			8.5	14	ns
$t_{pd1}$	E <sub>0</sub> thru E <sub>15</sub>	W			13	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

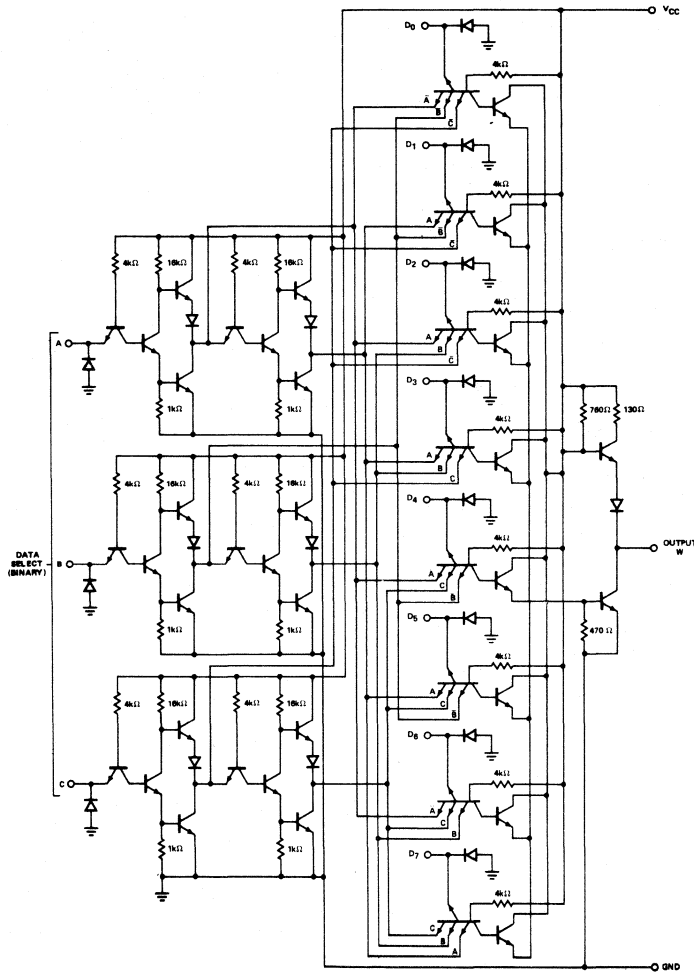
\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.



SIGNETICS 8-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER ■ S54152

SCHEMATIC DIAGRAM



Component values shown are nominal.

S54153-B,F,W • N74153-B,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

Each of these monolithic, data selectors/multiplexers contains inverters and drivers to supply fully complementary, on-chip, binary decoding data selection to the AND-OR-invert gates. Separate strobe inputs are provided for each of the two four-line sections.

These data selectors/multiplexers are fully compatible for use with most TTL and DTL circuits. Each diode-clamped input represents only one normalized Series 54/74 load, and full fan-out to 10 normalized Series 54/74 loads is available from each of the outputs in the low-level state. A fan-out to 20 normalized Series 54/74 loads is provided in the high-level state to facilitate connection of unused inputs to used inputs. Typical power dissipation is 180 milliwatts.

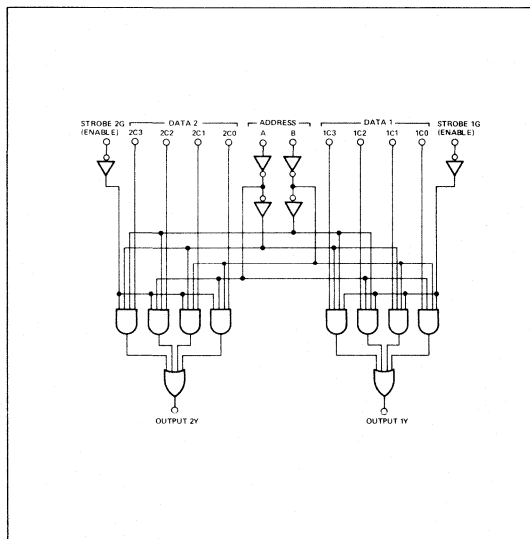
Resistor values in the OR function have been reduced to values used with Series 54H. This minimizes the capacitive effects of paralleling the phase-splitter transistors and reduces the propagation delay times. The S54153 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74153 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### TRUTH TABLE

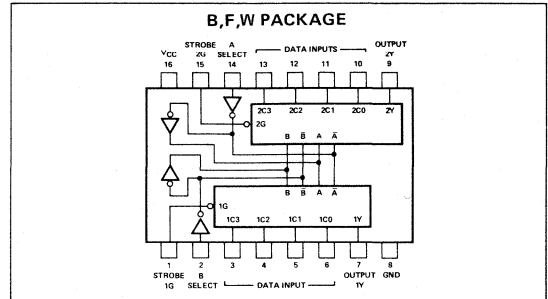
ADDRESS INPUTS		DATA INPUTS				STROBE	OUTPUT
B	A	C0	C1	C2	C3	G	Y
X	X	X	X	X	X	H	L
L	L	L	X	X	X	L	L
L	L	H	X	X	X	L	H
L	H	X	L	X	X	L	L
L	H	X	H	X	X	L	H
H	L	X	X	L	X	L	L
H	L	X	X	H	X	L	L
H	H	X	X	X	L	L	L
H	H	X	X	X	H	L	H

Address inputs A and B are common to both sections. H = high level, L = low level, X = irrelevant.

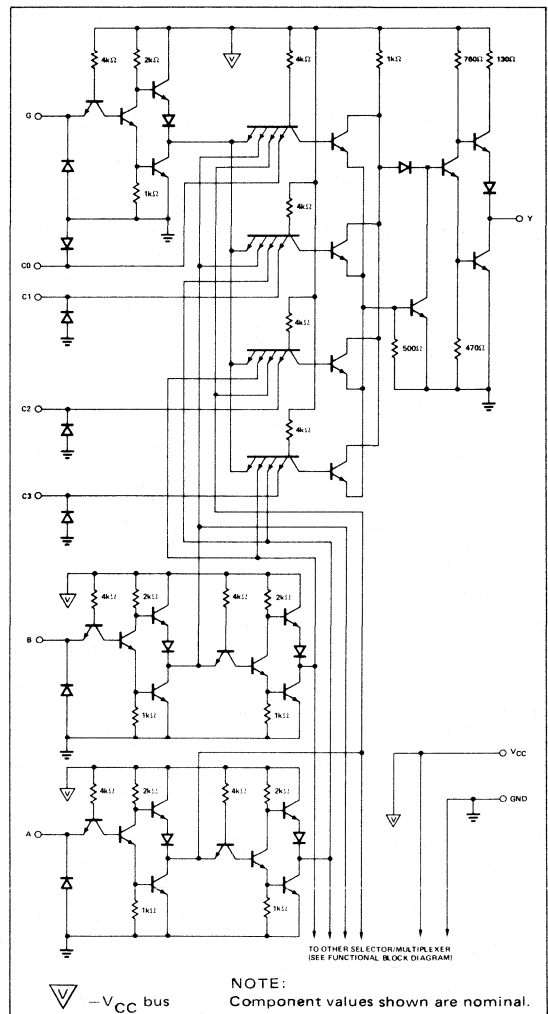
### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### SCHEMATIC DIAGRAM



# SIGNETICS DUAL 4-LINE TO 1-LINE DATA SELECTOR/MULTIPLEXER ■ S54153, N74153

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54153			N74153			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			20			20	
High Logic Level			10			10	
Low Logic Level			125			70	
Operating Free-Air Temperature Range, $T_A$	-55	25		0	25		°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN},$ $V_{IL} = 0.8\text{V},$ $I_{OH} = -800\mu\text{A}$	2.4	3.1	V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN},$ $V_{IH} = 2\text{V},$ $V_{IL} = 0.8\text{V},$ $I_{OL} = 16\text{mA}$		0.2	V
$I_{IH}$	High-level input current (each input)	$V_{CC} = \text{MAX},$ $V_I = 2.4\text{V}$		40	$\mu\text{A}$
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MAX},$ $V_I = 5.5\text{V}$		1	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX},$ S54153	-20		mA
		N74153	-18		mA
$I_{CCL}$	Supply current, low-level output	$V_{CC} = \text{MAX},$ S54153		36	mA
		N74153		36	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Data	Y	$C_L = 30\text{pF},$ $R_L = 400\Omega$		12	18	ns
$t_{PHL}$	Data	Y			15	23	ns
$t_{PLH}$	Address	Y			22	34	ns
$t_{PHL}$	Address	Y			22	34	ns
$t_{PLH}$	Strobe	Y			19	30	ns
$t_{PHL}$	Strobe	Y			15	23	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

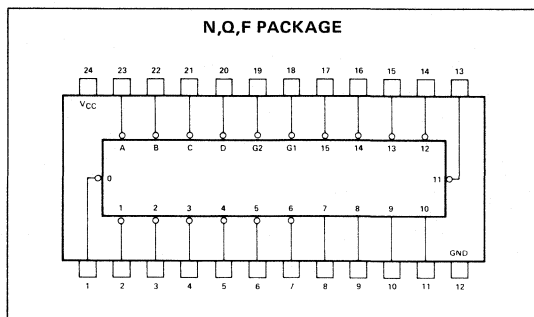
\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}.$

† Not more than one output should be shorted at a time.

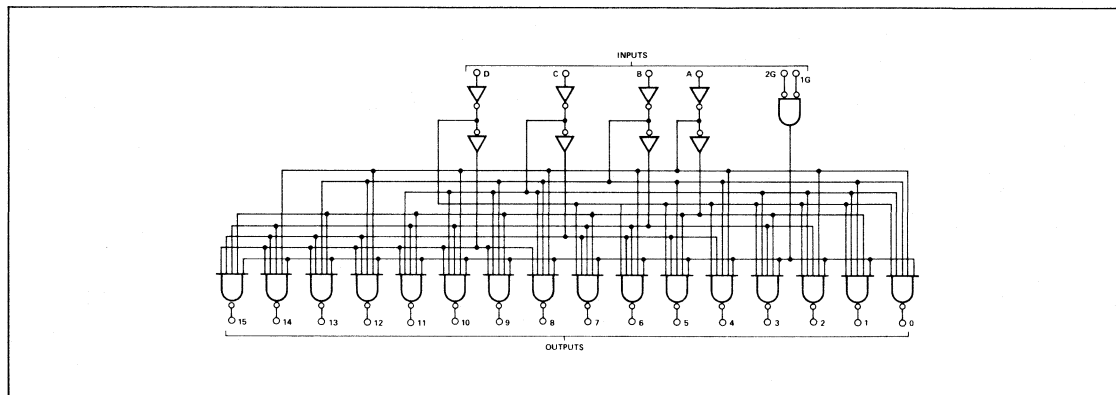
#### DESCRIPTION

The 54/74154 decodes 4 binary-coded inputs to one of 16 mutually exclusive outputs when each of the two strobe inputs are low. The demultiplexing function is achieved by using the 4 input lines for output addressing and data from one strobe input while the other strobe input is held low.

#### PIN CONFIGURATIONS



#### LOGIC DIAGRAM



#### TRUTH TABLE

INPUTS					OUTPUTS																	
G1	G2	D	C	B	A	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	
L	L	L	L	L	L	L	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H
L	L	L	L	L	H	H	L	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H
L	L	L	L	H	L	H	H	L	H	H	H	H	H	H	H	H	H	H	H	H	H	H
L	L	L	L	H	H	H	H	H	L	H	H	H	H	H	H	H	H	H	H	H	H	H
L	L	L	H	L	L	H	H	H	H	L	H	H	H	H	H	H	H	H	H	H	H	H
L	L	L	H	H	L	H	H	H	H	H	L	H	H	H	H	H	H	H	H	H	H	H
L	L	L	H	H	H	H	H	H	H	H	H	L	H	H	H	H	H	H	H	H	H	H
L	L	H	L	L	L	H	H	H	H	H	H	H	L	H	H	H	H	H	H	H	H	H
L	L	H	L	L	H	H	H	H	H	H	H	H	H	L	H	H	H	H	H	H	H	H
L	L	H	L	H	L	H	H	H	H	H	H	H	H	H	L	H	H	H	H	H	H	H
L	L	H	L	H	H	H	H	H	H	H	H	H	H	H	L	H	H	H	H	H	H	H
L	L	H	H	L	L	H	H	H	H	H	H	H	H	H	H	L	H	H	H	H	H	H
L	L	H	H	H	L	H	H	H	H	H	H	H	H	H	H	H	L	H	H	H	H	H
L	L	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	L	H	H	H	H
L	L	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	L	H	H	H
L	H	X	X	X	X	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H
H	L	X	X	X	X	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H
H	H	X	X	X	X	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H	H

H = High, L = Low, X = Irrelevant

# SIGNETICS 4-LINE TO 16-LINE DECODER/DEMULTIPLEXER ■ S54154, N74154

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54154			N74154			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:			10			10	
Low logic level			20			20	
High logic level			20			20	
Operating Free-Air Temperature Range	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2V,$ $V_{IL} = 0.8V, I_{OH} = -800 \mu A$	2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2V,$ $V_{IL} = 0.8V, I_{OL} = 16mA$			0.4	V
$I_{IH}$ High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.4V$ $V_{CC} = \text{MAX}, V_I = 5.5V$			40	A
				1	mA
$I_{IL}$ Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.4V$			-1.6	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = \text{MAX}$				mA
					mA
					mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$				mA
					mA
					mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$ Propagation delay time, low-to-high-level output, from A, B, C, or D inputs through 3 levels of logic			24	36	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output, from A, B, C, or D inputs through 3 levels of logic	$C_L = 15pF,$ $R_L = 400\Omega$		22	33	ns
$t_{PLH}$ Propagation delay time, low-to-high-level output, from either strobe input			20	30	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output, from either strobe input			18	27	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable circuit type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

### DESCRIPTION

These monolithic transistor-transistor-logic (TTL) circuits feature dual 1-line to 4-line demultiplexers with individual strobes and common binary-address inputs in a single 16-pin package. When both sections are enabled by the strobes, the common binary-address inputs sequentially select and route associated input data to the appropriate output of each section. The individual strobes permit activating or inhibiting each of the 4-bit sections as desired.

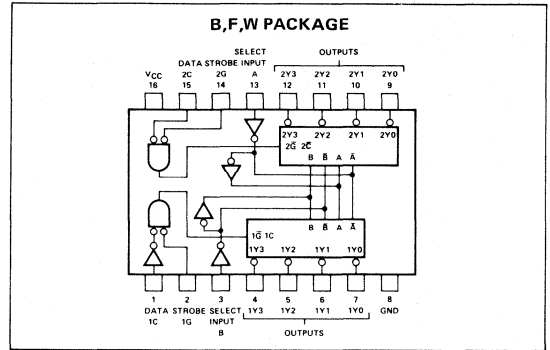
Data applied to input 1C is inverted at its outputs and data applied at 2C is not inverted through its outputs. The inverter following the 1C data input permits use as a 3- to 8-line decoder without external gating. See typical applications data and the truth tables for more details.

The S54155/N74155 circuits, with totem pole outputs, are rated to fan-out to 10 normalized Series 54/74 loads in the low-level output state, and to 20 loads in the high-level output state. The S54156/N74156 circuits, with open-collector outputs, are rated to sink 16 milliamperes at a low-level output voltage of less than 0.4 volt. Input-clamping diodes are provided on all of these circuits to minimize transmission-line effects and simplify system design.

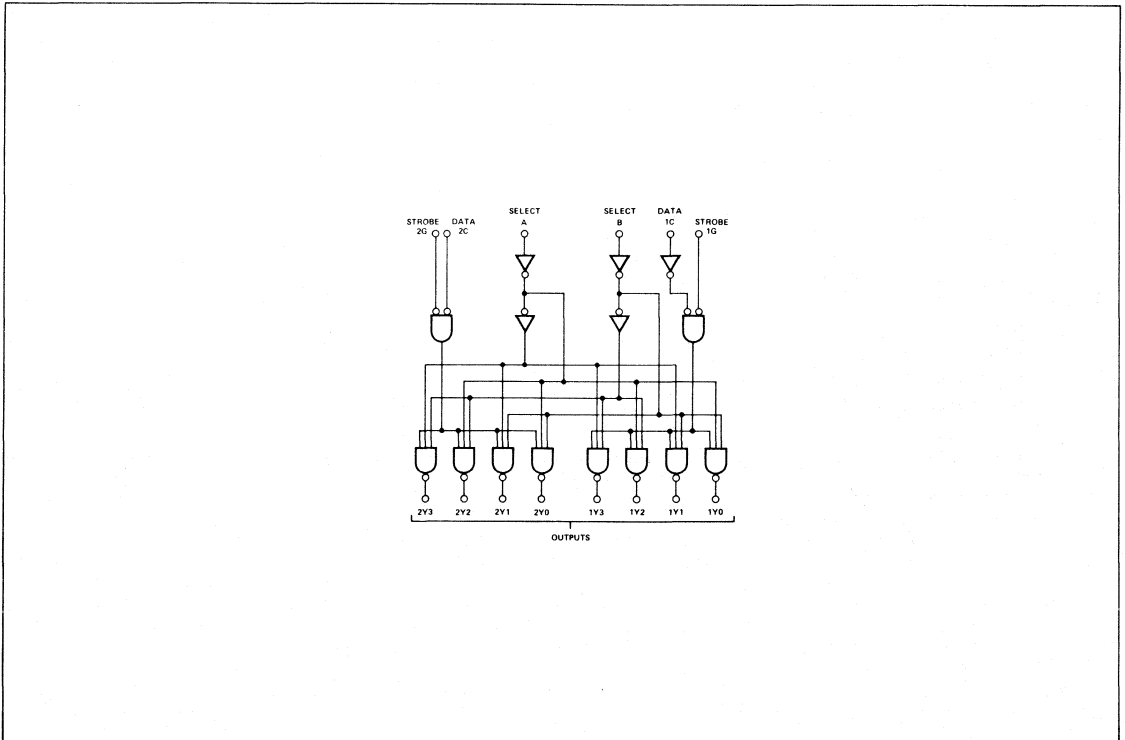
Typical power dissipation is 125 milliwatts. Typical average propagation delay times are 16 nanoseconds through 2 levels of logic and 21 nanoseconds through 3 levels of logic for the S54155/N74155.

The S54155 and S54156 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$  the N74155 and N74156 are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### PIN CONFIGURATION



### LOGIC DIAGRAM



# SIGNETICS DUAL 2-LINE TO 4-LINE DECODER/DEMULTIPLEXER ■ S54/N74155, S54/N74156

## TRUTH TABLES

TRUTH TABLES (H = High Level, L = Low Level, X = Irrelevant)

**2-LINE TO 4-LINE DECODER OR 1-LINE TO 4-LINE DEMULTIPLEXER**

INPUTS				OUTPUTS				INPUTS				OUTPUTS			
SELECT		STROBE	DATA	1Y0	1Y1	1Y2	1Y3	SELECT		STROBE	DATA	2Y0	2Y1	2Y2	2Y3
B	A	1G	1C					B	A	2G	2C				
X	X	H	X	H	H	H	H	X	X	H	X	H	H	H	H
L	L	L	H	L	H	H	H	L	L	L	L	L	H	H	H
L	H	L	H	H	L	H	H	L	H	L	L	H	L	H	H
H	L	L	H	H	H	L	H	H	L	L	L	H	H	L	H
H	H	L	H	H	H	H	L	H	H	L	L	H	H	H	L
X	X	X	L	H	H	H	H	X	X	X	H	H	H	H	H

**3-LINE TO 8-LINE DECODER TO 1-LINE TO 8-LINE DEMULTIPLEXER**

INPUTS				OUTPUTS							
SELECT			STROBE OR DATA	(0)	(1)	(2)	(3)	(4)	(5)	(6)	(7)
C <sup>†</sup>	B	A	G <sup>‡</sup>	2Y0	2Y1	2Y2	2Y3	1Y0	1Y1	1Y2	1Y3
X	X	X	H	H	H	H	H	H	H	H	H
L	L	L	L	L	H	H	H	H	H	H	H
L	L	H	L	H	L	H	H	H	H	H	H
L	H	L	L	H	H	L	H	H	H	H	H
L	H	H	L	H	H	H	L	H	H	H	H
H	L	L	L	H	H	H	H	L	H	H	H
H	L	H	L	H	H	H	H	H	L	H	H
H	H	L	L	H	H	H	H	H	H	L	H
H	H	H	L	H	H	H	H	H	H	H	L

<sup>†</sup>C = inputs 1C and 2C connected together

<sup>‡</sup>G = inputs 1G and 2G connected together

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54155			N74155			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: High logic level			20			20	
Low logic level			10			10	
Operating Free-Air Temperature Range, T <sub>A</sub>	-55	25	125	0	25	70	°C

PARAMETER	S54156			N74156			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
Low-level Output Current, I <sub>OL</sub>			16			16	mA
Operating Free-Air Temperature Range, T <sub>A</sub>	-55	25	125	0	25	70	°C

# SIGNETICS DUAL 2-LINE TO 4-LINE DECODER/DEMULTIPLEXER ■ S54/N74155, S54/N74156

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	S54155, N74155			UNIT
		MIN	TYP**	MAX	
V <sub>IH</sub> High-level input voltage		2			V
V <sub>IL</sub> Low-level input voltage				0.8	V
V <sub>OH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, I <sub>OH</sub> = -800μA	2.4			V
V <sub>OL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8V, I <sub>OL</sub> = 16mA			0.4	V
I <sub>IH</sub> High-level input current (each input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4V			40	μA
	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1	mA
I <sub>IL</sub> Low-level input current (each input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4V			-1.6	mA
I <sub>OS</sub> Short-circuit output current †	V <sub>CC</sub> = MAX	S54155 N74155	-20 -18	-55 -57	mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX	S54155 N74155	25 25	35 40	mA

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	S54156, N74156			UNIT
		MIN	TYP**	MAX	
V <sub>IH</sub> High-level input voltage		2			V
V <sub>IL</sub> Low-level input voltage				0.8	V
I <sub>OH</sub> High-level output current	V <sub>CC</sub> = MIN, V <sub>I</sub> = 2V, V <sub>OH</sub> = 5.5V			250	μA
V <sub>OL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8V, I <sub>OL</sub> = 16mA			0.4	V
I <sub>IH</sub> High-level input current (each input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4V			40	μA
	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1	mA
I <sub>IL</sub> Low-level input current (each input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4V			-1.6	mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX	S54156 N74156	25 25	35 40	mA

SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C, N = 10

PARAMETER †	FROM (INPUT)	TO (OUTPUT)	LEVELS OF LOGIC	TEST CONDITIONS	S54155 N74155		S54156 N74156		UNIT
					MIN	TYP	MIN	TYP	
t <sub>PLH</sub>	A, B, 2C, 1G, or 2G	Y	2		13	20	15	23	ns
t <sub>PHL</sub>	A, B, 2C, 1G, or 2G	Y	2	C <sub>L</sub> = 15pF,	18	27	20	30	ns
t <sub>PLH</sub>	A or B	Y	3	R <sub>L</sub> = 400Ω	21	32	23	34	ns
t <sub>PHL</sub>	A or B	Y	3		21	32	23	34	ns
t <sub>PLH</sub>	1C	Y	3		16	24	18	27	ns
t <sub>PHL</sub>	1C	Y	3		20	30	22	33	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.

† Not more than one output should be shorted at a time.

‡ t<sub>PLH</sub> = propagation delay time, low-to-high-level output

t<sub>PHL</sub> = propagation delay time, high-to-low-level output



# SIGNETICS DUAL 2-LINE TO 4-LINE DECODER/DEMULTIPLEXER ■ S54/N74155, S54/N74156

## TYPICAL APPLICATION DATA

The S54155, N74155, S54156, or N74156 may be used as a dual 2-line to 4-line decoder or a 1-line to 4-line demultiplexer. These applications are identical except as follows:

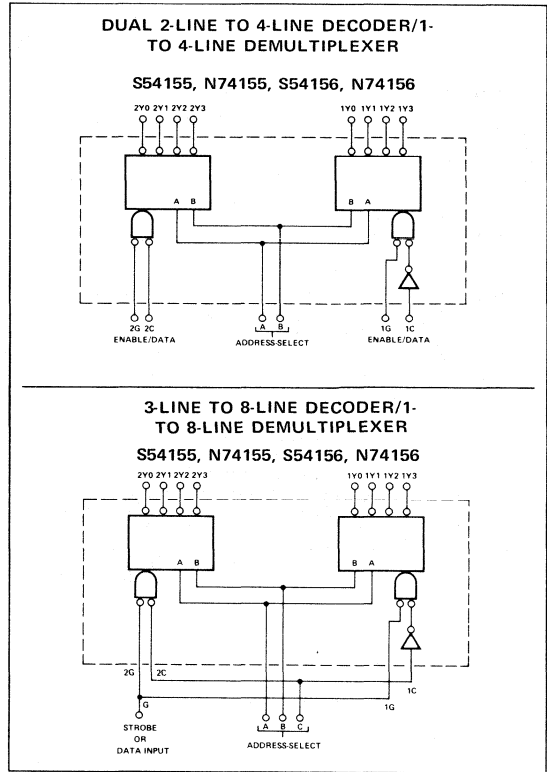
When decoding, the 2-line code is applied to select inputs A and B. The 4-line output section (1Y0, 1Y1, 1Y2, 1Y3) is enabled by taking strobe 1G low and input 1C high. The other 4-line output section (2Y0, 2Y1, 2Y2, 2Y3) is enabled by taking both strobe 2G and input 2C low. Note that the separate enable lines permit the user complete flexibility in decoding at either or both of the output sections. The strobe also permits cascading and allows disabling of the circuits until the addressing transients have passed.

When demultiplexing, the serial data is applied to the data inputs 1C and 2C and distribution to the outputs is controlled by the A and B select inputs. Again, the separate strobe inputs, 1G and 2G, permit demultiplexing to occur at either or both output sections, and cascading.

Any of these circuits may also be used as a 3-line to 8-line decoder or a 1-line to 8-line demultiplexer.

When used as a decoder, data inputs 1C and 2C are connected together and serve as the third (C) select line. The strobes are also connected together and are used for enabling and/or cascading.

When used as a demultiplexer, the common strobe line serves as the data input.



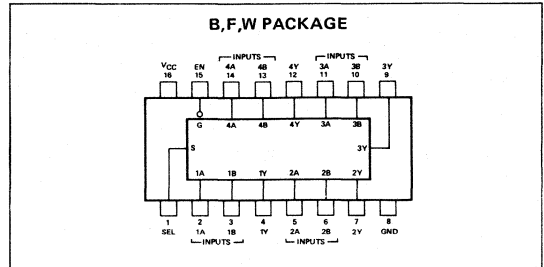
S54157-B,F,W • N74157-B,F • S54158-B,F,W • N74158-B,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The S54157/N74157 and S54158/N74158 are identical with the exception of the S54158/N74158 being inverted. These devices are logical implementations of a four-pole two-position switch, with the position of the switch being set by the logic levels supplied to the one select input. Both assertion and negation outputs are provided. The enable input (E) is active low. When it is not activated the negation output is high and the assertion output is low regardless of all other inputs. The devices provide the ability, in one package, to select four bits of either data or control from two sources. By proper manipulation of the inputs, it can generate four functions of two variables with one variable common. Thus any number of random logic elements used to generate unusual truth tables can be replaced. All outputs are low when disabled (enable high). Both inputs and outputs are buffered.

### PIN CONFIGURATION



S54/N74157

TRUTH TABLE

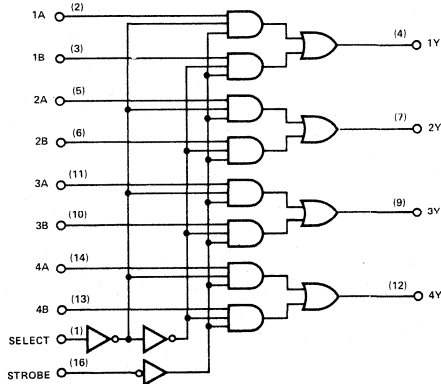
STROBE	INPUTS		OUTPUT
	SELECT	A B	
H	X	X X	L
L	L	L X	L
L	L	H X	H
L	H	X L	L
L	H	X H	H

S54/N74158

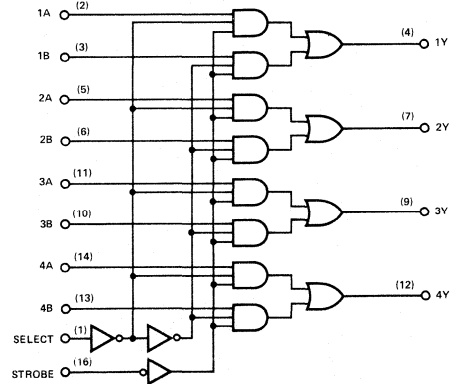
TRUTH TABLE

STROBE	INPUTS		OUTPUT
	SELECT	A B	
H	X	X X	H
L	L	L X	H
L	L	H X	L
L	H	X L	H
L	H	X H	L

LOGIC DIAGRAM  
S54/N74157



LOGIC DIAGRAM  
S54/N74158



# SIGNETICS QUADRUPLE 2-INPUT DATA SELECTOR/MULTIPLEXER ■ S54/N74157, S54/N74158

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54157/58			N74157/58			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			20			20	
High Logic Level			10			10	
Low Logic Level			125			70	
Operating Free-Air Temperature, $T_A$	-55	25		0	25		°C

## ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54157/58			N74157/58			UNIT
		MIN	TYP**	MAX	MIN	TYP**	MAX	
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.8			0.8	V
$V_I$	Input clamp voltage			-1.5			-1.5	V
$V_{OH}$	High-level output voltage	2.4			2.4			V
$V_{OL}$	Low-level output voltage			0.4			0.4	V
$I_I$	Input current at maximum input voltage			1			1	mA
$I_{IH}$	High-level input current			40			40	μA
$I_{IL}$	Low-level input current			-1.6			-1.6	mA
$I_{OS}$	Short-circuit output current†	-20		-55	-18		-55	mA
$I_{CC}$	Supply current		30	48		30	48	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^\circ C$ , $N = 10$

PARAMETER	FROM	TO	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PHL}$	Data	Output	$C_L = 15pF$ , $R_L = 400$		9	14	ns
$t_{PLH}$	Data	Output			9	14	ns
$t_{PHL}$	Enable	Any Output			14	21	ns
$t_{PLH}$	Enable	Any Output			13	20	ns
$t_{PHL}$	Select	Any Output			18	27	ns
$t_{PLH}$	Select	Any Output			15	23	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

S54160-B,F,W • S54161-B,F,W • S54162-B,F,W • S54163-B,F,W  
 N74160-B,F • N74161-B,F • N74162-B,F • N74163-B,F

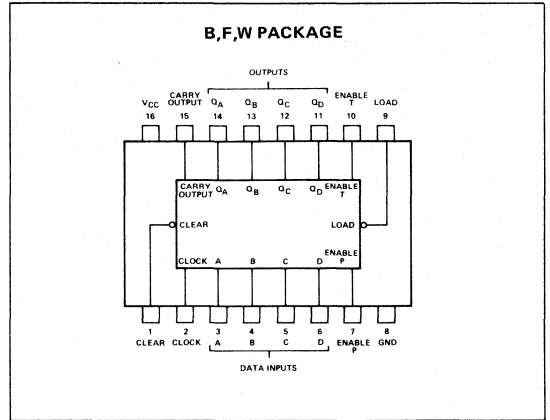
DIGITAL 54/74 TTL SERIES

### DESCRIPTION

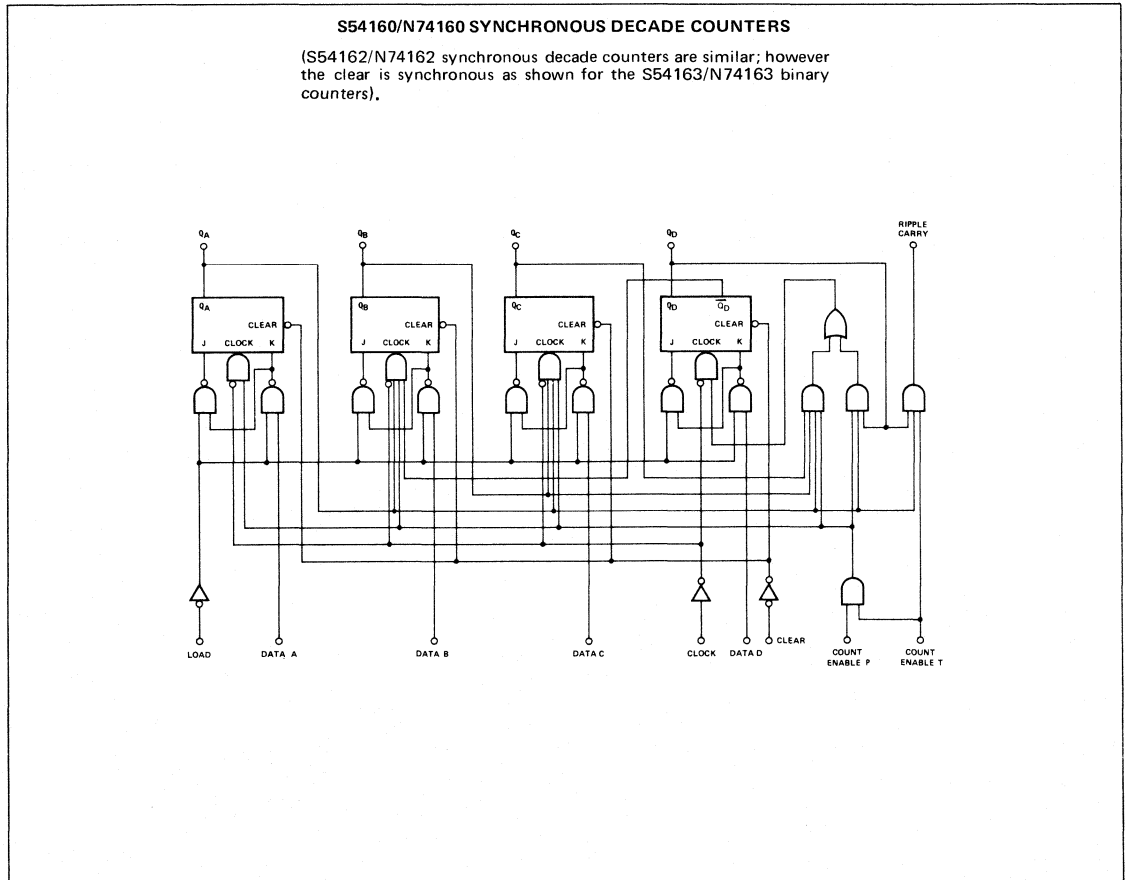
These synchronous, presettable counters feature an internal carry look-ahead for application in high-speed counting schemes. The S54160, S54162, N74160, and N74162 are decade counters and the S54161, S54163, N74161, and N74163 are 4-bit binary counters. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincident with each other when so instructed by the count-enable inputs and internal gating. This mode of operation eliminates the output counting spikes which are normally associated with asynchronous (ripple clock) counters. A buffered clock input triggers the four J-K master-slave flip-flops on the rising (positive-going) edge of the clock input waveform.

All inputs are diode-clamped to minimize transmission-line effects, thereby simplifying system design. A full fan-out to ten normalized Series 54/74 loads is available from each of the outputs in the low-level state. A fan-out to 20 normalized Series 54/74 loads is provided in the high-level state to facilitate connection of unused inputs and power dissipation is typically 325 milliwatts.

### PIN CONFIGURATION

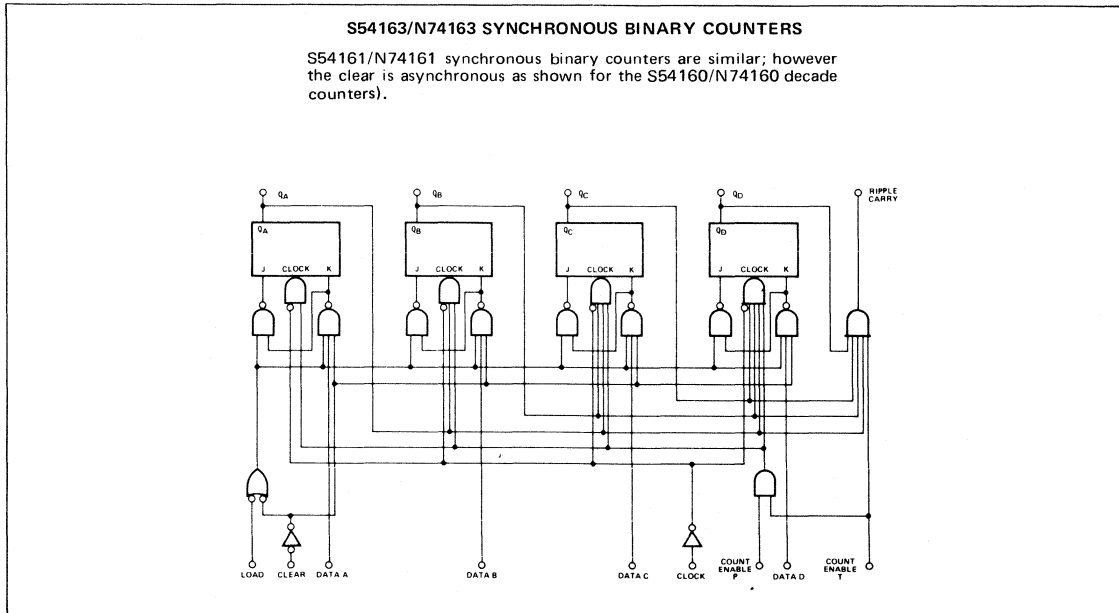


### LOGIC DIAGRAM



# SIGNETICS SYNCHRONOUS 4-BIT COUNTER ■ S54/N74160, S54/N74161, S54/N74162, S54/N74163

## LOGIC DIAGRAM (Cont'd)



## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54160, S54161 S54162, S54163			N74160, N74161 N74162, N74163			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level			20			MHz
Low logic level			10				
Input Clock Frequency, $f_{clock}$	0		25	0		25	ns
Width of Clock Pulse, $t_w(clock)$	25		25	25		25	ns
Width of Clear Pulse, $t_w(clear)$	20		20	20		20	ns
Setup Time, $t_{setup}$ :	Data Inputs, A,B,C,D			15			ns
Enable P			20				
Load			25				
Clear			20				
Hold Time at any Input, $t_{hold}$	0		0	0		0	ns
Operating Free-Air Temperature, $T_A$	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise specified)

PARAMETER	TEST CONDITIONS*	S54160,S54161 S54162,S54163			N74160,N74161 N74162,N74163			UNIT
		MIN	TYP**	MAX	MIN	TYP**	MAX	
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.8			0.8	V
$V_I$	Input clamp voltage			-1.5			-1.5	V
$V_{OH}$	High-level output voltage	2.4			2.4			V
$V_{OL}$	Low-level output voltage			0.4			0.4	V
$I_I$	Input current at maximum input voltage			1			1	mA
$I_{IH}$	High-level Clock or enable T input current Other inputs			80			80	μA
$I_{IL}$	Low-level Clock or enable T input current Other inputs			40			40	μA
$I_{IH}$	High-level Clock or enable T input current Other inputs			-3.2			-3.2	mA
$I_{IL}$	Low-level Clock or enable T input current Other inputs			-1.6			-1.6	mA
$I_{OS}$	Short-circuit output current†	-20		-57	-18		-57	mA
$I_{CC}$	Supply current, all outputs high		See Note 3	85		59	94	mA
$I_{CC}$	Supply current, all outputs low		See Note 4	63		63	101	mA

# SIGNETICS SYNCHRONOUS 4-BIT COUNTER ■ S54/N74160, S54/N74161, S54/N74162, S54/N74163

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

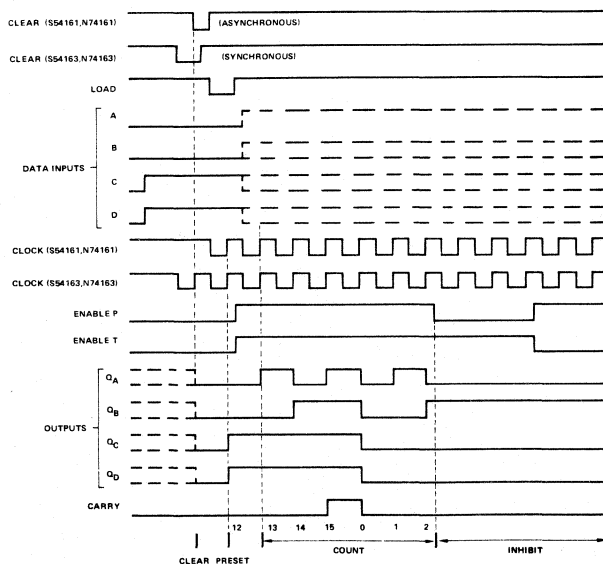
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum input clock frequency		25	32		MHz
$t_{PLH}$	Propagation delay time, low-to-high-level carry output from clock			23	35	ns
$t_{PHL}$	Propagation delay time, high-to-low-level carry output from clock			23	35	ns
$t_{PLH}$	Propagation delay time, low-to-high-level Q output from clock (load input high)			13	20	ns
$t_{PHL}$	Propagation delay time, high-to-low-level Q output from clock (load input high)	$C_L = 15 \text{ pF}$ ,		15	23	ns
$t_{PLH}$	Propagation delay time, low-to-high-level carry output from enable T	$R_L = 400 \Omega$		10	14	ns
$t_{PHL}$	Propagation delay time, high-to-low-level carry output from enable T			10	14	ns
$t_{PHL}$	Propagation delay time, high-to-low-level Q output from clear			20	30	ns
$t_{PLH}$	Propagation delay time, low-to-high-level Q output from clock (load input low)			17	25	ns
$t_{PHL}$	Propagation delay time, high-to-low-level Q output from clock (load input low)			19	29	ns

- NOTES:
1. Propagation delay for clearing is measured from the clear input for the '160 and '161 or from the clock input transition for the '162 and '163.
  2. See waveforms in Figures 1 and 2. Load circuit is shown on page 148.

## TYPICAL CLEAR, PRESET, COUNT, AND INHIBIT SEQUENCES FOR 54161, 74161, 54163, 74163 SYNCHRONOUS BINARY COUNTERS

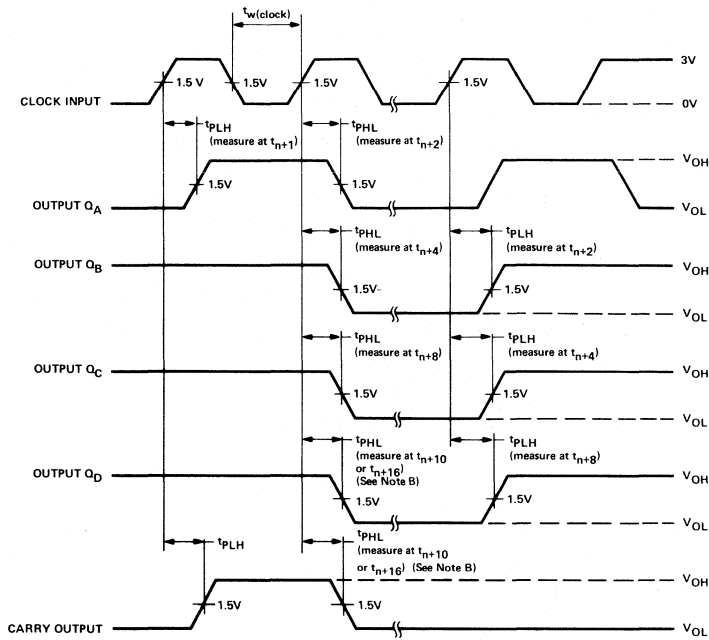
Illustrated below is the following sequence:

1. Clear outputs to zero.
2. Preset to binary twelve.
3. Count to thirteen, fourteen, fifteen, zero, one, and two.
4. Inhibit.



PARAMETER MEASUREMENT INFORMATION

VOLTAGE WAVEFORMS

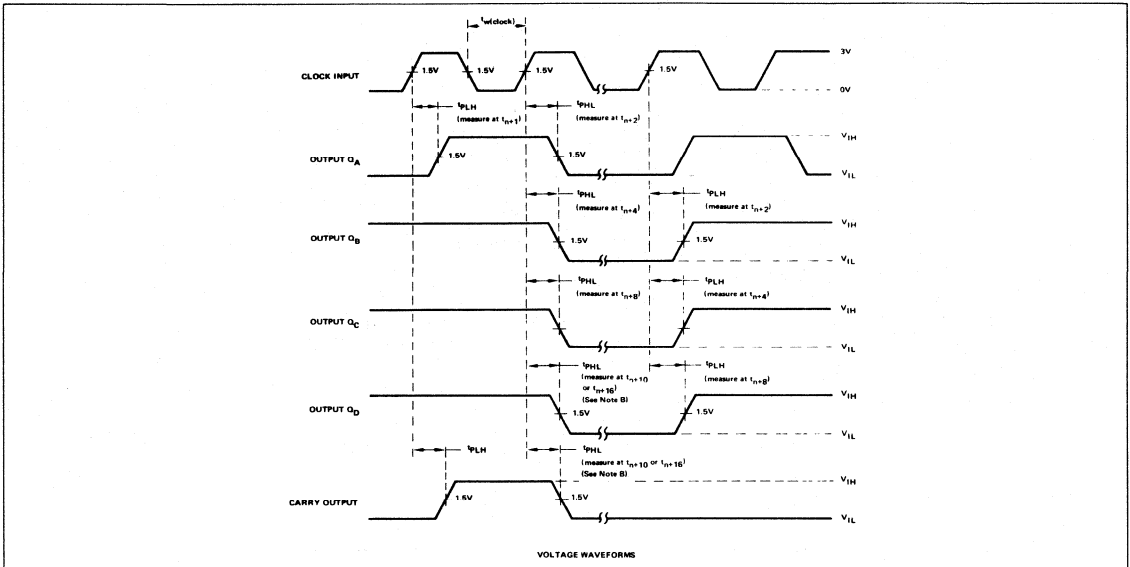


NOTES:

1. The input pulses are supplied by a generator having the following characteristics:  $t_r \leq 10\text{ns}$ ,  $t_f \leq 10\text{ns}$ ,  $\text{PRR} \leq 1\text{MHz}$ , duty cycle  $\leq 50\%$ ,  $Z_{\text{out}} \approx 50\Omega$ . Vary PRR to measure  $f_{\text{max}}$ .
2. Outputs  $Q_D$  and carry are tested at  $t_{n+10}$  for the N54160, N54162, N74160, and N74162, and at  $t_{n+16}$  for the N54161, N54163, N74161, and N74163, where  $t_n$  is the bit time when all outputs are low.

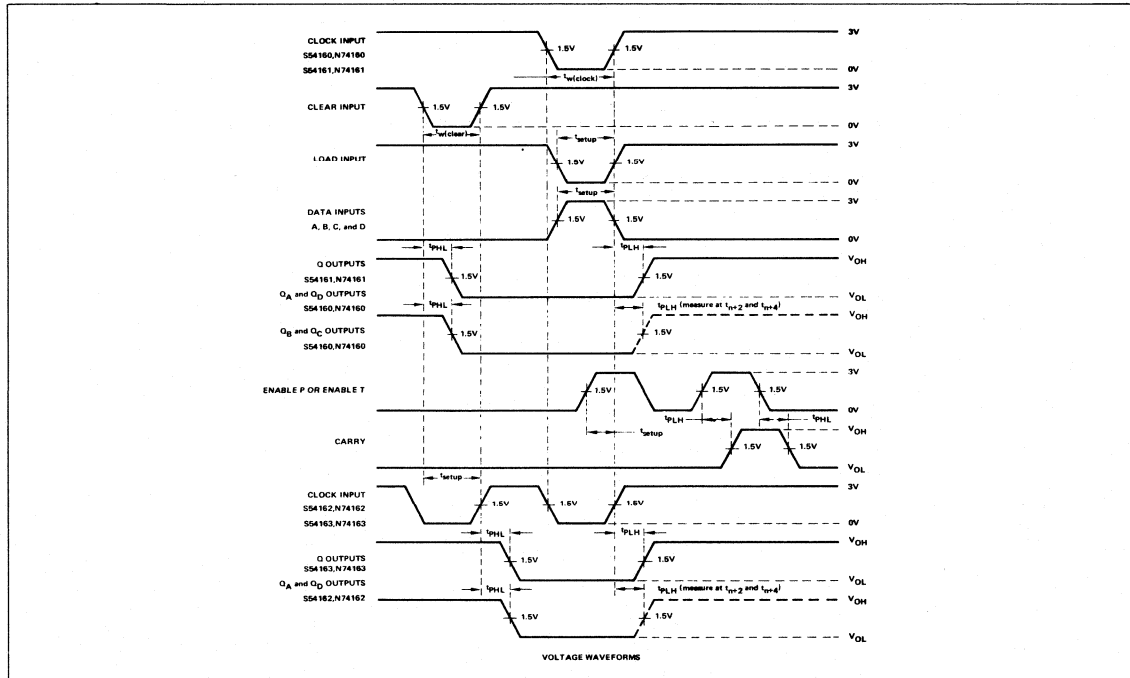
**SIGNETICS SYNCHRONOUS 4-BIT COUNTER ■ S54/N74160, S54/N74161, S54/N74162, S54/N74163**

**PARAMETER MEASUREMENT INFORMATION**



**NOTES:**

- The input pulses are supplied by a generator having the following characteristics:  $t_r \leq 10ns$ ;  $t_f \leq 10ns$ ;  $PRR \leq 1\text{ MHz}$ , duty cycle  $\leq 50\%$ ,  $Z_{out} \approx 50\Omega$ . Vary PRR to measure  $t_{max}$ .
- Outputs  $Q_D$  and carry are tested at  $t_{n+10}$  for the S54160, S54162, N74160, and N74162, and at  $t_{n+16}$  for the S54161, S54163, N74161, and N74163, where  $t_n$  is the bit time when all outputs are low.



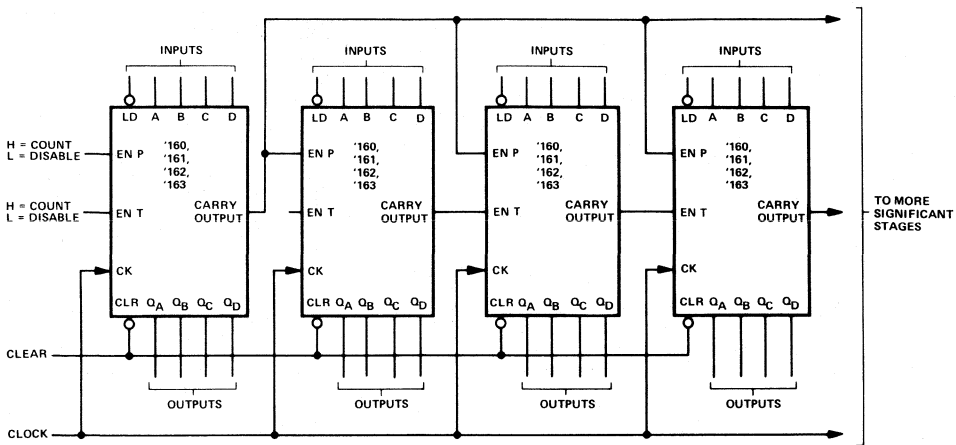
**NOTES:**

- The input pulses are supplied by a generator having the following characteristics:  $t_r \leq 10ns$ ;  $t_f \leq 10ns$ ;  $PRR \leq 1\text{ MHz}$ , duty cycle  $\leq 50\%$ ;  $Z_{out} \approx 50\Omega$ .
- Enable P and enable T setup times are measured at  $t_n = 0$ .



TYPICAL APPLICATION DATA

N-BIT SYNCHRONOUS COUNTERS USING '160, '161, '162 and '163 COUNTERS



This application demonstrates how the look-ahead carry circuit can be used to implement a high speed n-bit counter. The '160 or '162 will count in BCD and the '161 or '163 will count in binary. Virtually any count mode (modulo-N, N<sub>1</sub>-to-N<sub>2</sub>, N<sub>1</sub>-to-maximum) can be used with this fast look-ahead scheme.

S54164-A,F • N74164-A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These 8-bit shift registers feature gated serial inputs and an asynchronous clear. The gated serial inputs (A and B) permit complete control over incoming data as a low at either (or both) input(s) inhibits entry of the new data and resets the first flip-flop to the low level at the next clock pulse. A high-level input enables the other input which will then determine the state of the first flip-flop. Data at the serial inputs may be changed while the clock is high, but only information meeting the setup requirements will be entered. Clocking occurs on the low-to-high-level transition of the clock input.

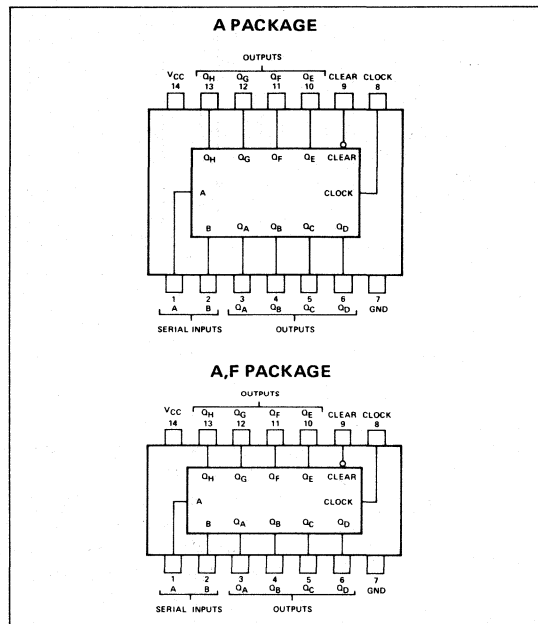
All inputs are diode-clamped to minimize transmission-line effects, and are buffered to represent only one Series 54/74 load which simplifies system design. Power dissipation is typically 21 milliwatts per bit. Maximum input clock frequency is typically 36 megahertz.

The S54164 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74164 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

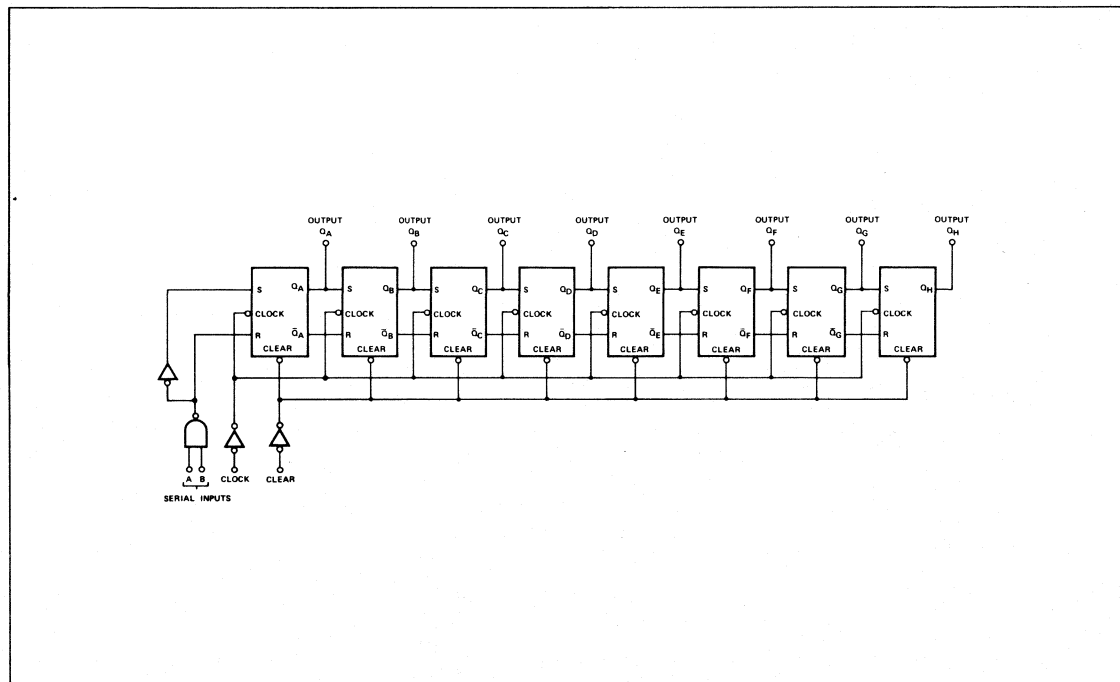
### TRUTH TABLE

SERIAL INPUTS A AND B		
INPUTS		OUTPUT
A	B	$Q_A$
H	H	H
L	H	L
H	L	L
L	L	L

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



# SIGNETICS 8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS ■ S54164, N74164

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54164			N74164			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level			10			10
	Low logic level			5			5
Input Clock Frequency, $f_{clock}$	0		25	0		25	MHz
Width of Clock or Clear Input Pulse, $t_w$	20			20			ns
Data Setup Time, $t_{setup}$	15			15			ns
Data Hold Time, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54164			N74164			UNIT
		MIN	TYP**	MAX	MIN	TYP**	MAX	
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage	0.8			0.8			V
$V_I$	Input clamp voltage	-1.5			-1.5			V
$V_{OH}$	High-level output voltage	2.4			2.4			V
$V_{OL}$	Low-level output voltage	0.4			0.4			V
$I_I$	Input current at maximum input voltage	1			1			mA
$I_{IH}$	High-level input current	40			40			μA
$I_{IL}$	Low-level input current	-1.6			-1.6			mA
$I_{OS}$	Short-circuit output current †	-10			-9			mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			mA
		$V_{CC} = \text{MAX}, V_{I(\text{clock})} = 0.4\text{V}$			$V_{CC} = \text{MAX}, V_{I(\text{clock})} = 0.4\text{V}$			30
		See Note $V_{I(\text{clock})} = 2.4\text{V}$			See Note $V_{I(\text{clock})} = 2.4\text{V}$			37 54

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 5$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum input count frequency	25	36		MHz
$t_{PHL}$	Propagation delay time, high-to-low-level Q outputs from clear input		24	36	ns
	Propagation delay time, low-to-high-level Q outputs from clock input	8	17	27	ns
$t_{PLH}$	Propagation delay time, high-to-low-level Q outputs from clock input	10	20	30	ns
	Propagation delay time, low-to-high-level Q outputs from clear input	10	21	32	ns
$t_{PHL}$	Propagation delay time, high-to-low-level Q outputs from clear input	10	25	37	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

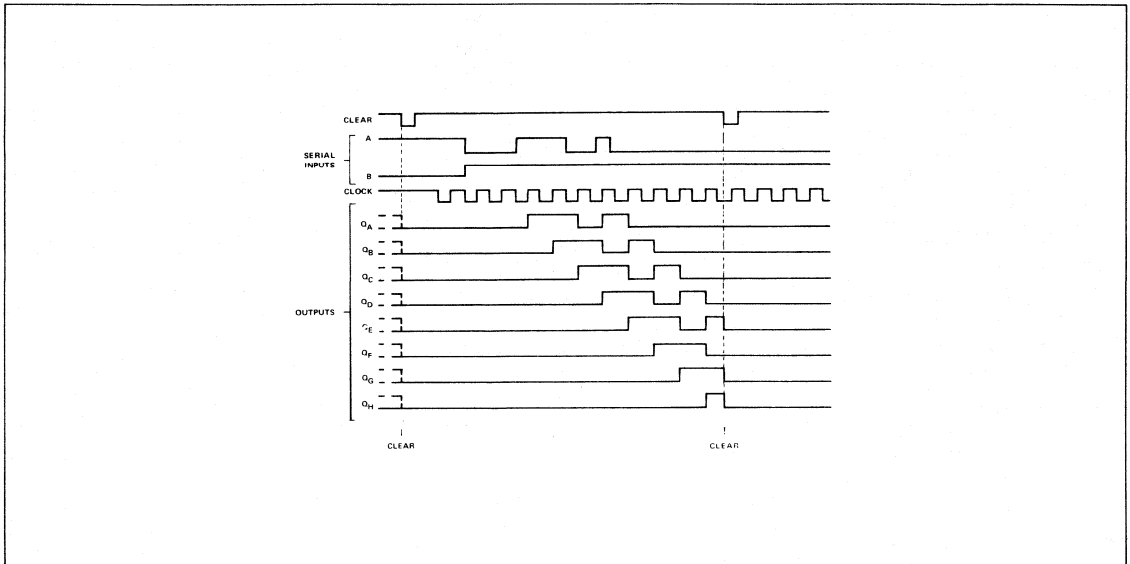
\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than two outputs should be shorted at a time.

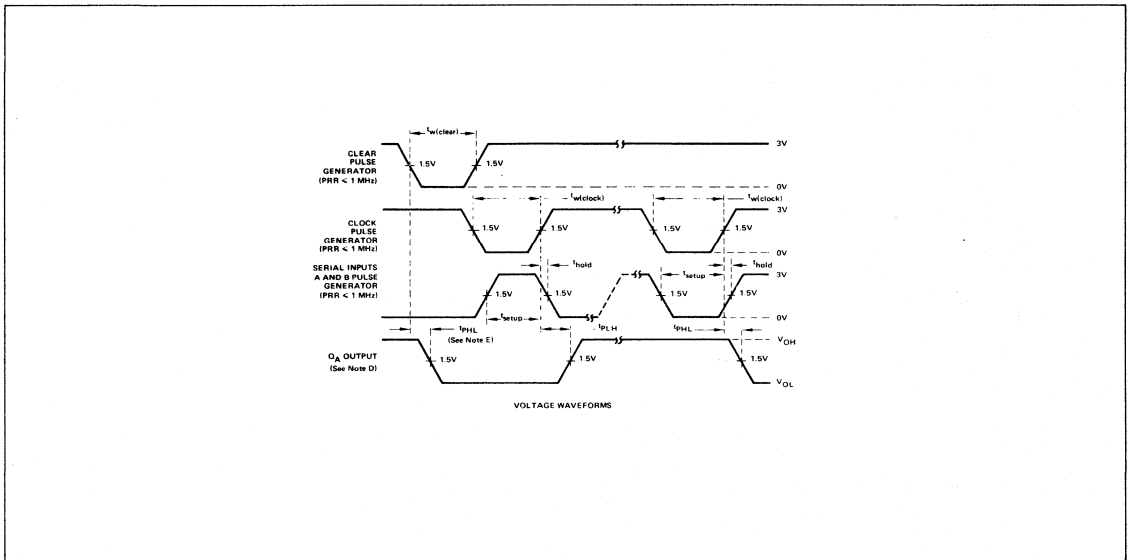
NOTE:  $I_{CC}$  is measured with outputs open, serial inputs grounded and a momentary ground, then 4.5V, applied to clear.

# SIGNETICS 8-BIT PARALLEL-OUT SERIAL SHIFT REGISTERS ■ S54164, N74164

## TYPICAL CLEAR, INHIBIT, SHIFT, CLEAR, AND INHIBIT SEQUENCES



## PARAMETER MEASUREMENT INFORMATION



- NOTES:
- The pulse generators have the following characteristics:  $t_r \leq 10ns$ ,  $t_f \leq 10ns$ , duty cycle  $\leq 50\%$ ,  $Z_{out} \approx 50\Omega$ .
  - $C_L$  includes probe and jig capacitance.
  - All diodes are 1N3064.
  - $Q_A$  output is illustrated. Relationship of serial input A and B data to other Q outputs is illustrated in the typical shift sequence.
  - Outputs are set to the high level prior to the measurement of  $t_{PHL}$  from the clear input.

S54165—B,F,W • N74165—B, F

DIGITAL 54/74 TTL SERIES

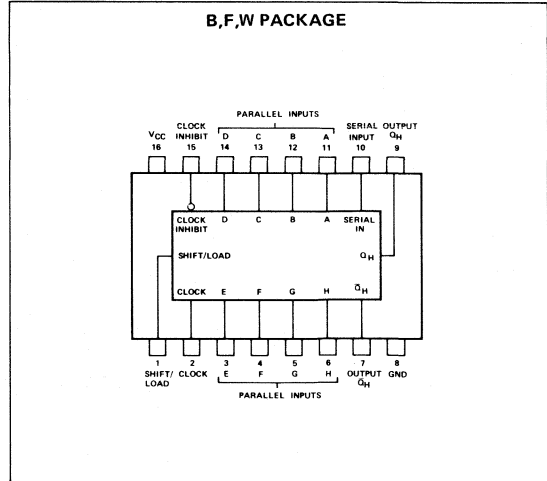
### DESCRIPTION

The S54165 and N74165 are 8-bit serial shift registers that shift data to the right when clocked. Parallel-in access to each stage is made available by eight individual direct data inputs which are enabled by a low level at the shift/load input. These registers also feature gated clock inputs and complementary outputs from the eighth bit.

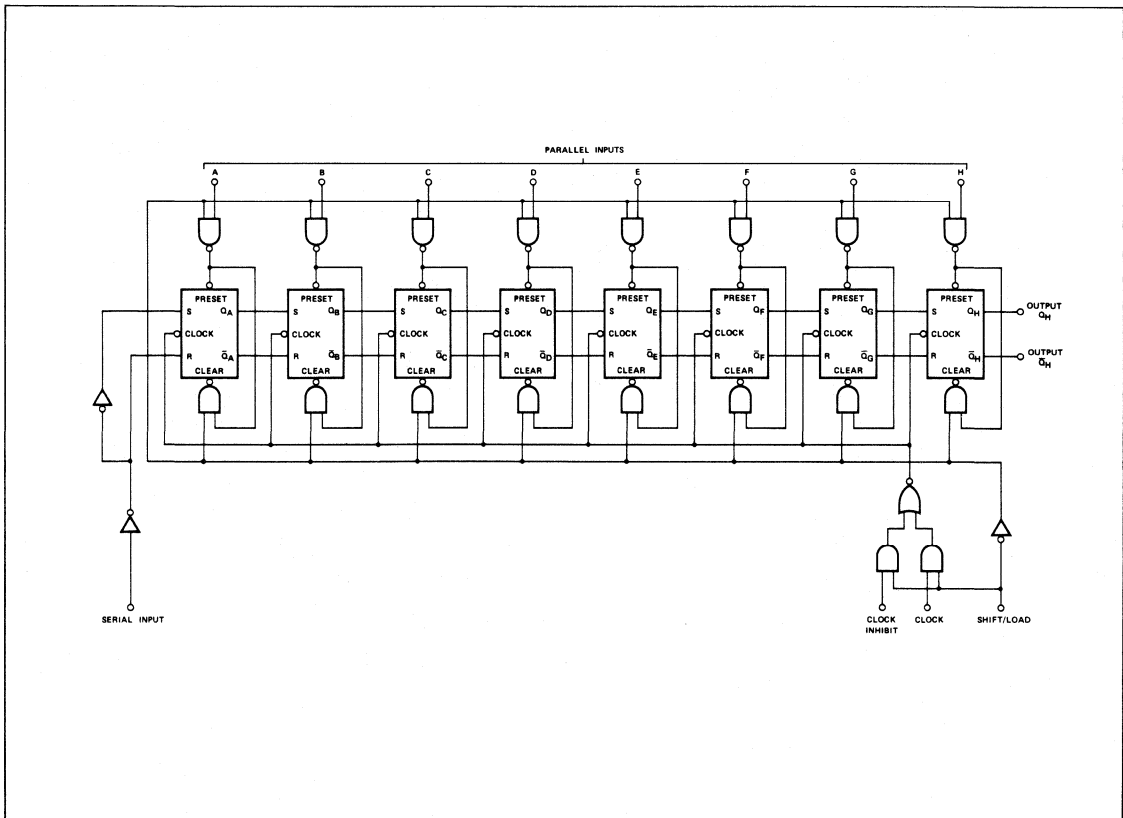
Clocking is accomplished through a 2-input positive-NOR gate, permitting one input to be used as a clock-inhibit function. Holding either of the clock inputs high inhibits clocking, and holding either clock input low with the load input high enables the other clock input. The clock-inhibit input should be changed to the high level only while the clock input is high. Parallel loading is inhibited as long as the load input is high. When taken low, data at the parallel inputs are loaded directly into the register independently of the state of the clock.

All inputs are diode-clamped to minimize transmission-line effects, thereby simplifying system design. Power dissipation is typically 210 milliwatts and maximum input clock frequency is typically 26 megahertz. The S54165 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74165 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



# SIGNETICS PARALLEL-LOAD 8-BIT SHIFT REGISTER ■ S54165, N74165

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54165			N74165			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level			20			20
	Low logic level			10			10
Input Clock Frequency, $f_{clock}$	0		20	0		20	MHz
Width of Clock Input Pulse, $t_w(\text{clock})$	25			25			ns
Width of Load Input Pulse, $t_w(\text{load})$	15			15			ns
Clock-Enable Setup Time, $t_{setup}$	30			30			ns
Parallel Input Setup Time, $t_{setup}$	10			10			ns
Serial Input Setup Time, $t_{setup}$	20			20			ns
Shift Setup Time, $t_{setup}$	45			45			ns
Hold Time at any Input, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	S54165			N74165			UNIT
		MIN	TYP*	MAX	MIN	TYP*	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage				-1.5			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MAX}, I_I = -12 \text{ mA}$				2.4			V
	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V},$ $V_{IL} = 0.8 \text{ V}, I_{OH} = -800 \mu\text{A}$	2.4						V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V},$ $V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$			0.4			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1			1	mA
$I_{IH}$ High-level input current	Load Input Other inputs			80			80	$\mu\text{A}$
				40			40	$\mu\text{A}$
$I_{IL}$ Low-level input current	Load input Other inputs			-3.2			-3.2	mA
				-1.6			-1.6	mA
$I_{OS}$ Short-circuit output current †	$V_{CC} = \text{MAX}$	-20		-55	-18		-55	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}, \text{ See Note}$		42	63		42	63	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$				20	26		MHz
$t_{PLH}$	Load	Any	$C_L = 15 \text{ pF}, R_L = 400 \Omega,$		21	31	ns
$t_{PHL}$					27	40	
$t_{PLH}$	Clock	Any			16	27	ns
$t_{PHL}$					21	34	
$t_{PLH}$	H	$Q_H$			11	20	ns
$t_{PHL}$					24	36	
$t_{PLH}$	H	$\bar{Q}_H$			18	27	ns
$t_{PHL}$					18	27	

NOTE : With the outputs open, clock inhibit and shift/load at 4.5 V, and a clock pulse applied to the clock input,  $I_{CC}$  is measured first with the parallel inputs at 4.5 V, then with the parallel inputs grounded.

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\* All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

$f_{max}$  ≡ Maximum input count frequency

$t_{PLH}$  ≡ Propagation delay time, low-to-high-level output

$t_{PHL}$  ≡ Propagation delay time, high-to-low-level output

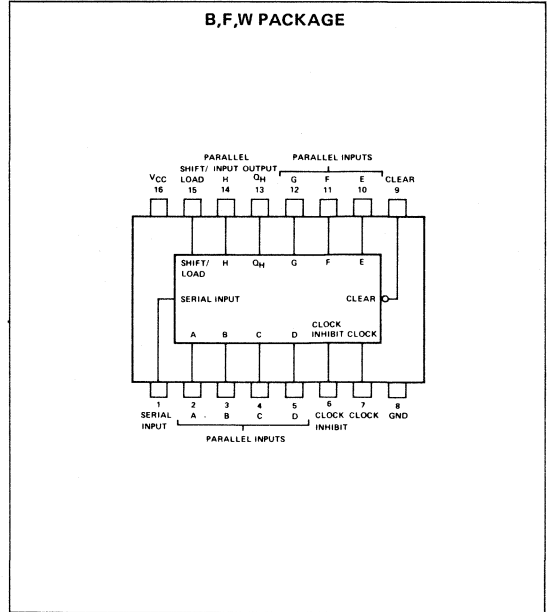
### DESCRIPTION

These 8-bit shift registers are compatible with most other TTL, DTL, and MSI logic families. All inputs are buffered to lower the drive requirements to one normalized Series 54/74 load, and input clamping diodes minimize switching transients to simplify system design. Maximum input clock frequency is typically 35 megahertz and power dissipation is typically 360 mW.

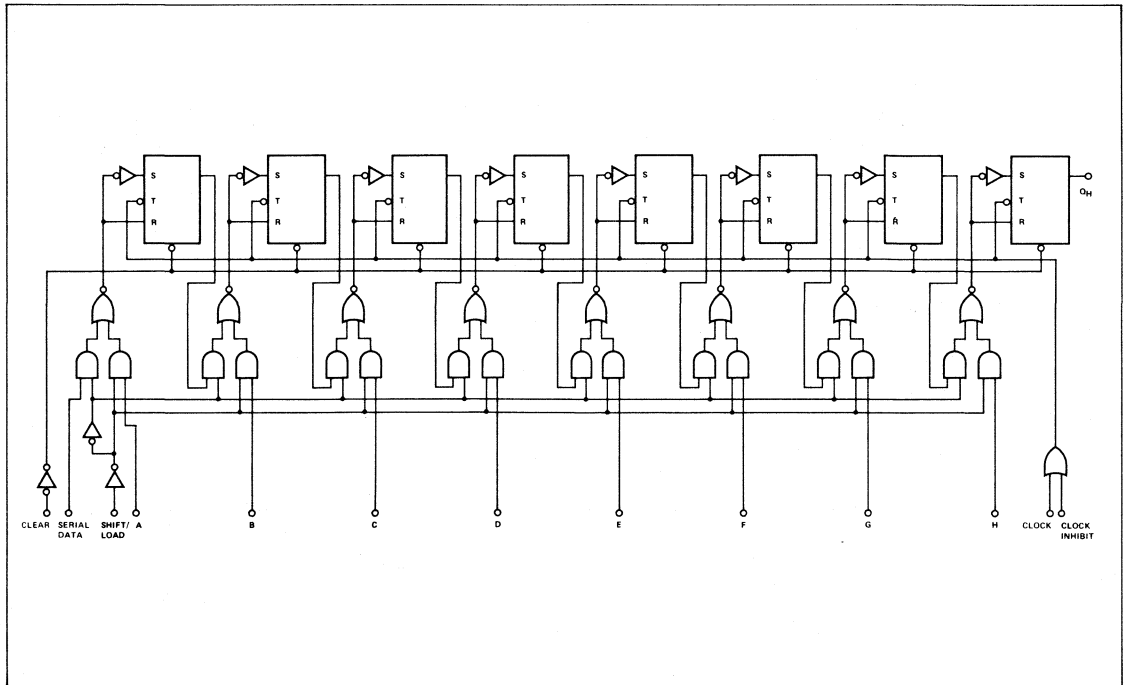
All Series 54 devices are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . Series 74 devices are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

These parallel-in or serial-in, serial-out shift registers have a complexity of 77 equivalent gates on a monolithic chip. They feature gated clock inputs and an overriding clear input. The parallel-in or serial-in modes are established by the shift/load input. When high, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. When low, the parallel (broadside) data inputs are enabled and synchronous loading occurs on the next clock pulse. During parallel loading, serial data flow is inhibited. Clocking is accomplished on the low-to-high-level edge of the clock pulse through a two-input positive NOR gate permitting one input to be used as a clock-enable or clock-inhibit function. Holding either of the clock inputs high inhibits clocking; holding either low enables the other clock input. This, of course, allows the system clock to be free-running and the register can be stopped on command with the gate input. The clock-inhibit input should be changed to the high level only while the clock input is high. A buffered, direct clear input overrides all other inputs, including the clock and sets all flip-flops to zero. Average power dissipation per gate is typically 4.7 mW.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



# SIGNETICS 8-BIT SHIFT REGISTER ■ S54166, N74166

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54166			N74166			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: High logic level			20			20	
Low logic level			10			10	
Input Count Frequency, $f_{count}$	0		25	0		25	MHz
Width of Clock or Clear Pulse, $t_w$	20			20			ns
Mode-Control Setup Time, $t_{setup}$	30			30			ns
Data Setup Time, $t_{setup}$	20			20			ns
Hold Time at any Input, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54166			N74166			UNIT
		MIN	TYP*	MAX	MIN	TYP*	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage	$V_{CC} = MAX, I_I = -12mA$			-1.5			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OH} = -800\mu A$	2.4			2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OL} = 16mA$			0.4			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = MAX, V_I = 5.5V$			1			1	mA
$I_{IH}$ High-level input current	$V_{CC} = MAX, V_I = 2.4V$			40			40	$\mu A$
$I_{IL}$ Low-level input current	$V_{CC} = MAX, V_I = 0.4V$			-1.6			-1.6	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = MAX$	-20		-57	-18		-57	mA
$I_{CC}$ Supply current	$V_{CC} = MAX, \text{Table Below}$		72	104		72	116	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum input count frequency		25	35		MHz
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear	$C_L = 15pF, R_L = 400\Omega$		23	35	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clock		8	20	30	ns
$t_{PLH}$ Propagation delay time, low-to-high-level output from clock		8	17	26	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

## TEST CONDITIONS FOR $I_{CC}$ (all outputs are open)

TYPE	APPLY 4.5V	FIRST GROUND, THEN APPLY 4.5V	GROUND
S54166, N74166	Serial Input	Clock	All other inputs



#### DESCRIPTION

The 54170 and 74170 MSI 16-bit TTL register files incorporate the equivalent of 98 gates on a monolithic chip. The register file is organized as 4 words of 4 bits each and separate on-chip decoding is provided for addressing the four word locations to either write-in or retrieve data. This permits simultaneous writing into one location and reading from another word location.

Four data inputs are available which are used to supply the 4-bit word to be stored. Location of the word is determined by the write address inputs A and B in conjunction with a write-enable signal. Data applied at the inputs should be in its true form. That is, if a high-level signal is desired for the output, a high-level is applied at the data input for that particular bit location. The latch inputs are arranged so that new data will be accepted only if both internal address gate inputs are high. When this condition exists, data at the D input is transferred to the latch output. When the write enable input,  $G_W$  is high, the data inputs are inhibited and their states can cause no change in the information stored in the internal latches. When the read enable output,  $G_R$ , is high, the data outputs are inhibited and remain high.

The individual address lines permit direct acquisition of data stored in any four of the latches. Four individual decoding gates

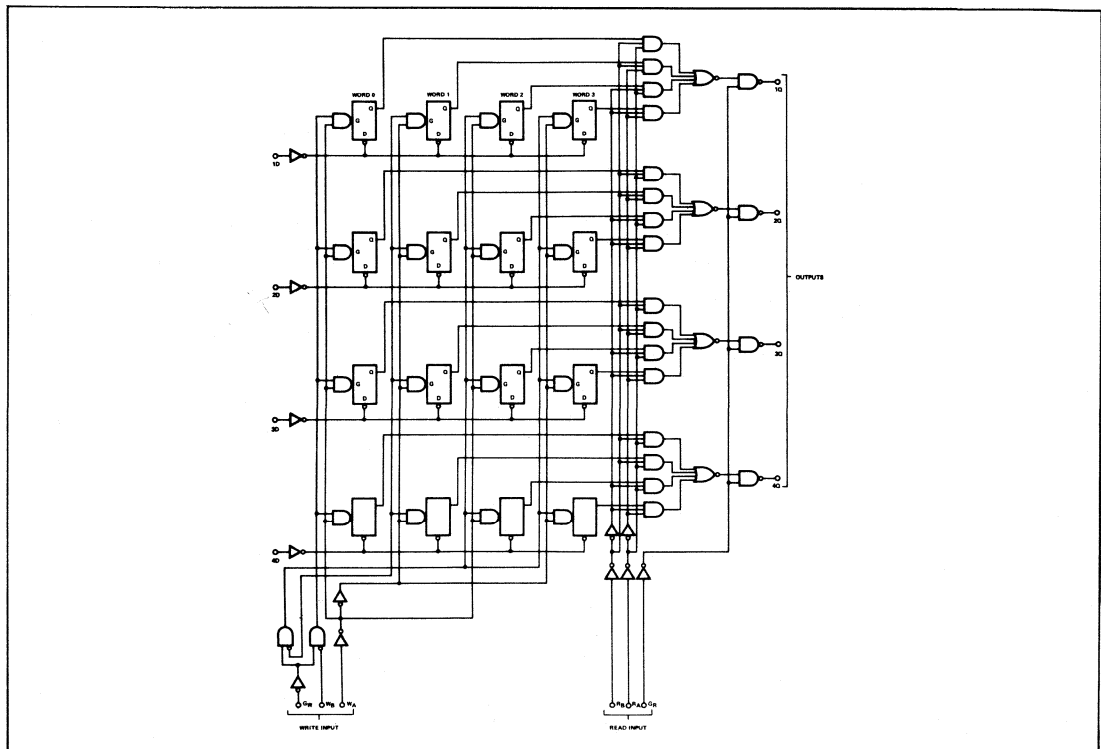
are used to complete the address for reading a word. When the read address is made in conjunction with the read-enable signal, the word appears at the four outputs.

This arrangement—data-entry addressing separate from data-read addressing and individual sense line—eliminates recovery times, permits simultaneous reading and writing, and is limited in speed only by the write time (45 nanoseconds maximum) and the read time (35 nanoseconds maximum). The register file has a non-destructive readout in that data is not lost when addressed.

All inputs are buffered to lower the drive requirements to one normalized Series 54/74 load, and input-clamping diodes minimize switching transients to simplify system design. High-speed, double-ended AND-OR-INVERT gates are employed for the read-address function and drive high-sink-current, open-collector outputs. Up to 256 of these outputs may be wire-AND connected for increasing the capacity up to 1024 words. Any number of these registers may be paralleled to provide n-bit word length.

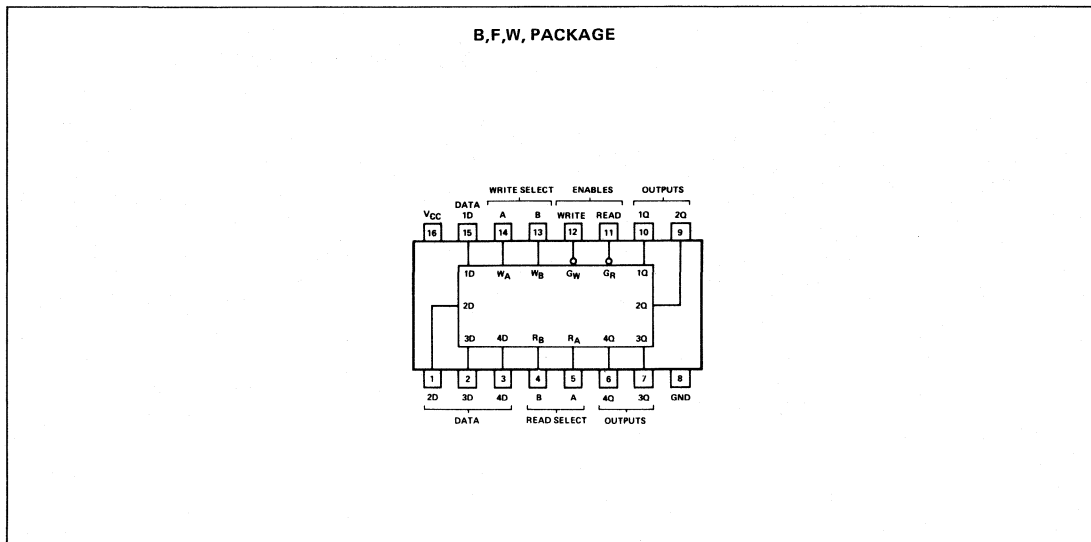
Power dissipation is typically 500 mW total or 5 mW per gate. The 54170 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 74170 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### LOGIC DIAGRAM



# SIGNETICS 4X4 REGISTER FILE ■ S54170, N74170

## PIN CONFIGURATION



## RECOMMENDED OPERATING CONDITIONS

PARAMETER	54170			74170			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Low-level output current, $I_{OL}$			16			16	mA
Width of write-enable or read-enable pulse, $t_w$	25			25			ns
Setup times, high- or low-level data (See Note 1)	data input with respect to write enable, $t_{setup}(D)$	10		10			ns
	write select with respect to write enable, $t_{setup}(W)$	15		15			ns
	read select with respect to read enable, $t_{setup}(R)$	5		5			ns
	data input with respect to write enable, $t_{hold}(D)$	0		0			ns
Hold times, high- or low-level data (See Note 2)	write select with respect to write enable, $t_{hold}(W)$	5		5			ns
	read select with respect to read enable, $t_{hold}(R)$	5		5			ns
Latch time for new data, $t_{latch}$ (See Note 3)	25			25			ns
Operating free-air temperature range, $T_A$	-55	25	125	0	25	70	°C

### NOTES:

1. Setup time is the interval immediately preceding the negative-going edge of the enable pulse during which interval the data or address to be recognized must be maintained at the input to ensure its recognition.
2. Hold time is the interval immediately following the positive-going edge of the enable pulse during which interval the data or address to be recognized must be maintained at the input to ensure its continued recognition.
3. Latch time is the time required for the internal output of the latch to assume the state of new data. See Figure 1. This is important only when attempting to read from a location immediately after that location has received new data.

# SIGNETICS 4x4 REGISTER FILE ■ S54170, N74170

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
V <sub>IH</sub>	High-level input voltage		2			V
V <sub>IL</sub>	Low-level input voltage				0.8	V
V <sub>I</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12 mA			-1.5	V
I <sub>OH</sub>	High-level output current	V <sub>CC</sub> = MIN, V <sub>O</sub> = 5.5 V			30	μA
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V I <sub>OL</sub> = 16 mA			0.4	V
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V			1	mA
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4 V			40	μA
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V			-1.6	mA
I <sub>CC</sub>	Supply current	V <sub>CC</sub> = MAX, 54170 see Note 6 74170		125 ‡	140	mA
				125 ‡	150	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

‡ Typical power dissipation shown is an average for 50% duty cycle at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

**NOTE 6:**

Maximum I<sub>CC</sub> is guaranteed for the following worst-case conditions: 4.5 V is applied to all data inputs and both enable inputs, all address inputs are grounded, and all outputs are open.

## SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output, from read enable to any Q	C <sub>L</sub> = 15 pF R <sub>L</sub> = 400 Ω		10	15	ns
t <sub>PHLq</sub>	Propagation delay time, high-to-low-level output, from read enable to any Q	C <sub>L</sub> = 15 pF R <sub>L</sub> = 400 Ω		20	30	ns

**LOGIC**

WRITE FUNCTION TABLE (SEE NOTES A, B, AND C)							
WRITE INPUTS			WORD				
W <sub>B</sub>	W <sub>A</sub>	G <sub>W</sub>	0	1	2	3	
L	L	L	Q = D	Q <sub>n</sub>	Q <sub>n</sub>	Q <sub>n</sub>	
L	H	L	Q <sub>n</sub>	Q = D	Q <sub>n</sub>	Q <sub>n</sub>	
H	L	L	Q <sub>n</sub>	Q <sub>n</sub>	Q = D	Q <sub>n</sub>	
H	H	L	Q <sub>n</sub>	Q <sub>n</sub>	Q <sub>n</sub>	Q = D	
X	X	H	Q <sub>n</sub>	Q <sub>n</sub>	Q <sub>n</sub>	Q <sub>n</sub>	

READ FUNCTION TABLE (SEE NOTES A AND D)							
READ INPUTS			OUTPUTS				
R <sub>B</sub>	R <sub>A</sub>	G <sub>R</sub>	1Q	2Q	3Q	4Q	
L	L	L	W0B1	W0B2	W0B3	W0B4	
L	H	L	W1B1	W1B2	W1B3	W1B4	
H	L	L	W2B1	W2B2	W2B3	W2B4	
H	H	L	W3B1	W3B2	W3B3	W3B4	
X	X	H	H	H	H	H	

**NOTES:**

A. H = high level, L = low level, X = irrelevant

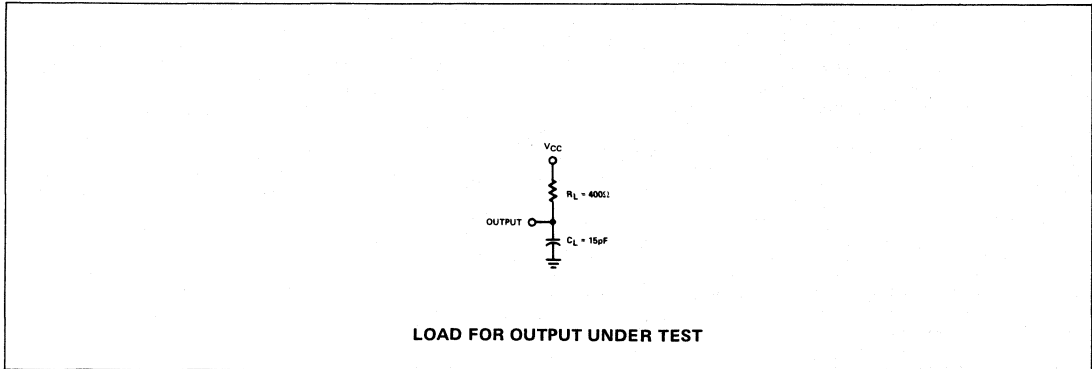
B. (Q = D) = The four selected internal flip-flop outputs will assume the states applied to the four external data inputs.

C. Q<sub>n</sub> = No change.

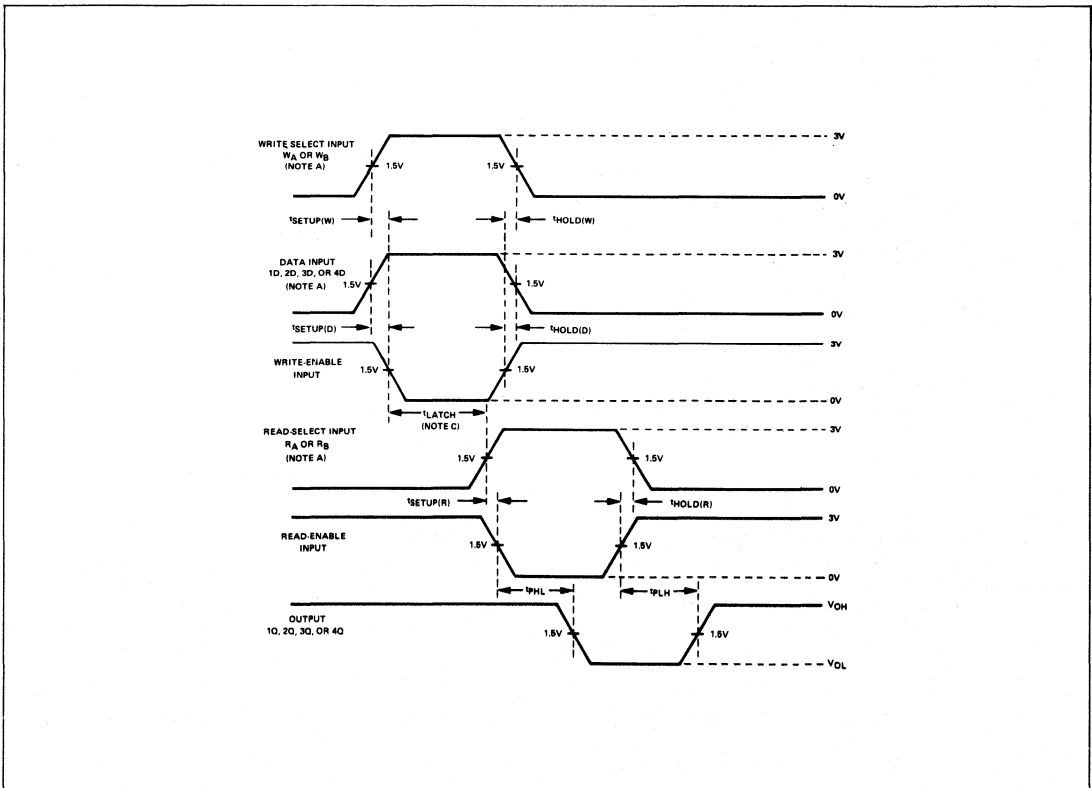
D. W0B1 = The first bit of word 0, etc.

# SIGNETICS 4X4 REGISTER FILE ■ S54170, N74170

## SWITCHING CHARACTERISTICS



## VOLTAGE WAVEFORMS



### NOTES:

- A. High-level inputs are illustrated; however, low-level setup and hold times are the same.
- B. Waveforms are supplied by generators with the following characteristics:  $PRR \leq 1\text{MHz}$ ,  $Z_{OUT} \approx 50\Omega$ , duty cycle  $\leq 50\%$ ,  $t_r \leq 10\text{ns}$ ,  $t_f = 10\text{ns}$ .
- C. This applies only when reading from a location immediately after that location has received new data.

## DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The 74172, containing the equivalent of 201 gates on a monolithic chip, is a high-performance 16-bit register file organized as eight words of two bits each.

Multiple address decoding circuitry is used so that the read and write operation can be performed independently on two word locations. This provides a true simultaneous read/write capability. Basically, the file consists of two distinct sections (see Figure 1).

Section 1 permits the writing of data into any two-bit word location while reading two bits of data from another location simultaneously. To provide this flexibility, independent decoding is incorporated.

Section 2 of the register file is similar to section 1 with the exception that common read/write address circuitry is employed. This means that section 2 can be utilized in one of three modes:

- 1) Writing new data into two bits
- 2) Reading from two bits
- 3) Writing into and simultaneously reading from the same two bits.

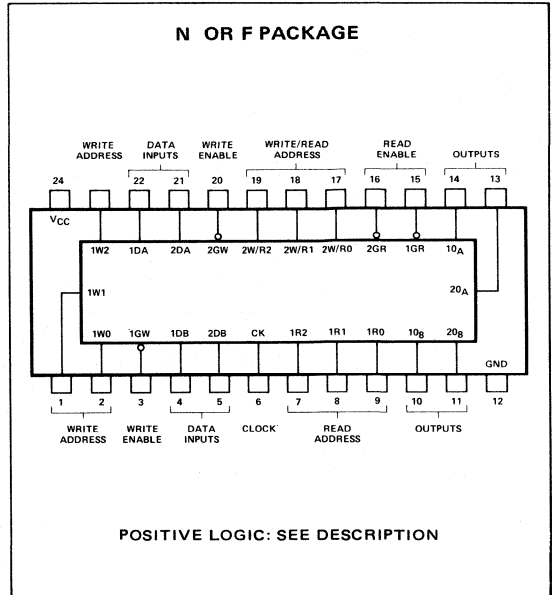
Regardless of the mode, the operation of section 2 is entirely independent of section 1.

The three-state outputs of this register file permit connection of up to 129 compatible outputs and one Series 54/74 high-logic-level load to a common system bus. The outputs are controlled by the read-enable circuitry so that they operate as standard TTL totem-pole outputs when the appropriate read-enabled input is low or they are placed in a high-impedance state when the associated read-enabled input is at a high logic level. To minimize the possibility that two outputs from separate register files will attempt to take a common bus to opposite logic levels, the read-enable circuitry is designed such that disable times are shorter than enable times.

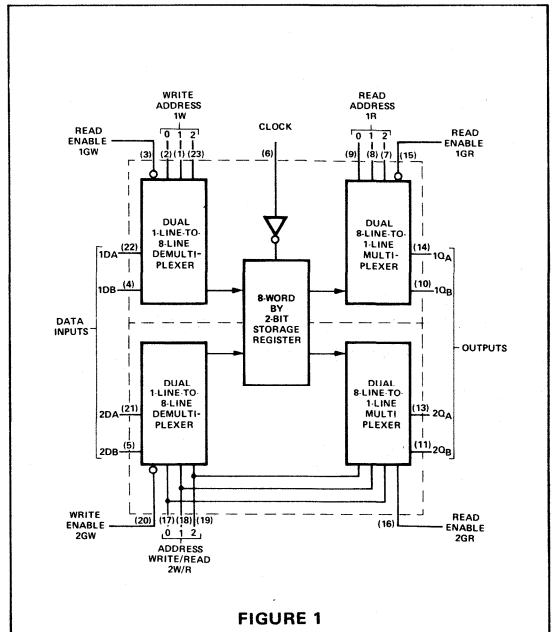
All inputs are buffered to lower the drive requirements of the clock, read/write address, and write-enable inputs to one normalized Series 54/74 load, and of all other inputs to one-half of one normalized Series 54/74 load.

Functions of the inputs and outputs of the 74172 are as shown in the following table.

### PIN CONFIGURATION



### BLOCK DIAGRAM



## FUNCTION TABLE

FUNCTION	SECTION 1	SECTION 2	DESCRIPTION
Write Address	1W0, 1W1, 1W2	2W/R0, 2W/R1, 2W/R2	Binary write address selects one of eight two-bit word locations.
Write Enable	1GW	2GW	When low, permits the writing of new data into the selected word location on a positive transition of the clock input.
Data Inputs	1DA, 1DB	2DA, 2DB	Data at these inputs is entered on a positive transition of the clock input into the location selected by the write address inputs if the write enable input is low. Since the two sections are independent, it is possible for both write functions to be activated with both write addresses selecting the same word location. If this occurs and the information at the data inputs is not the same for both sections (i.e., 1DA≠2DA and/or 1DB≠2DB) the low-level data will predominate in each bit and be stored.
Read Address	1R0, 1R1, 1R2	Common with write address	Binary write address selects one of eight two-bit word locations.
Read Enable	1GR	2GR	When read enable is low, the outputs assume the levels of the data stored in the location selected by read address inputs. When read enable is high, the associated outputs remain in the high-impedance state and neither significantly load nor drive the lines to which they are connected.
Data Outputs	1QA, 1QB	2QA, 2QB	
Clock	CK		The positive-going transition of the clock input will enter new data into the addressed location if the write enable input is low. The clock is common to both sections.

**ABSOLUTE MAXIMUM RATINGS.** (Over Operating Free-Air Temperature Range Unless Otherwise Noted).

Supply Voltage (See Note 1)	7 V
Input Voltage	5.5 V
Output Voltage (See Note 2)	5.5 V
Operating Free-Air Temperature Range	0°C to 70°C

Storage Temperature

-65°C to 150°C

**NOTES:**

1. Voltage values are with respect to network ground terminal.
2. This is the maximum voltage which should be applied to any output when it is in the high-impedance state.

RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply voltage, $V_{CC}$		4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level			130	
	Low logic level			.10	
Input clock frequency, $f_{clock}$		0		20	MHz
Width of clock pulse, $t_w(\text{clock})$		25			ns
Setup time, $t_{setup}$ (See Figure 1)	Write select	$t_w(\text{clock})+10$			ns
	High-level data	30			
	Low-level data	45			
	Write enable	35			
Hold time, $t_{hold}$ (See Figure 1)	Write select	0			ns
	Write enable	0			
Data release time, $t_{release}$ (See Figure 1)	High-level data			10	ns
	Low-level data			10	
Operating free-air temperature, $T_A$		0		70	°C

ELECTRICAL CHARACTERISTICS OVER RECOMMENDED OPERATING FREE-AIR TEMPERATURE RANGE (UNLESS OTHERWISE NOTED)

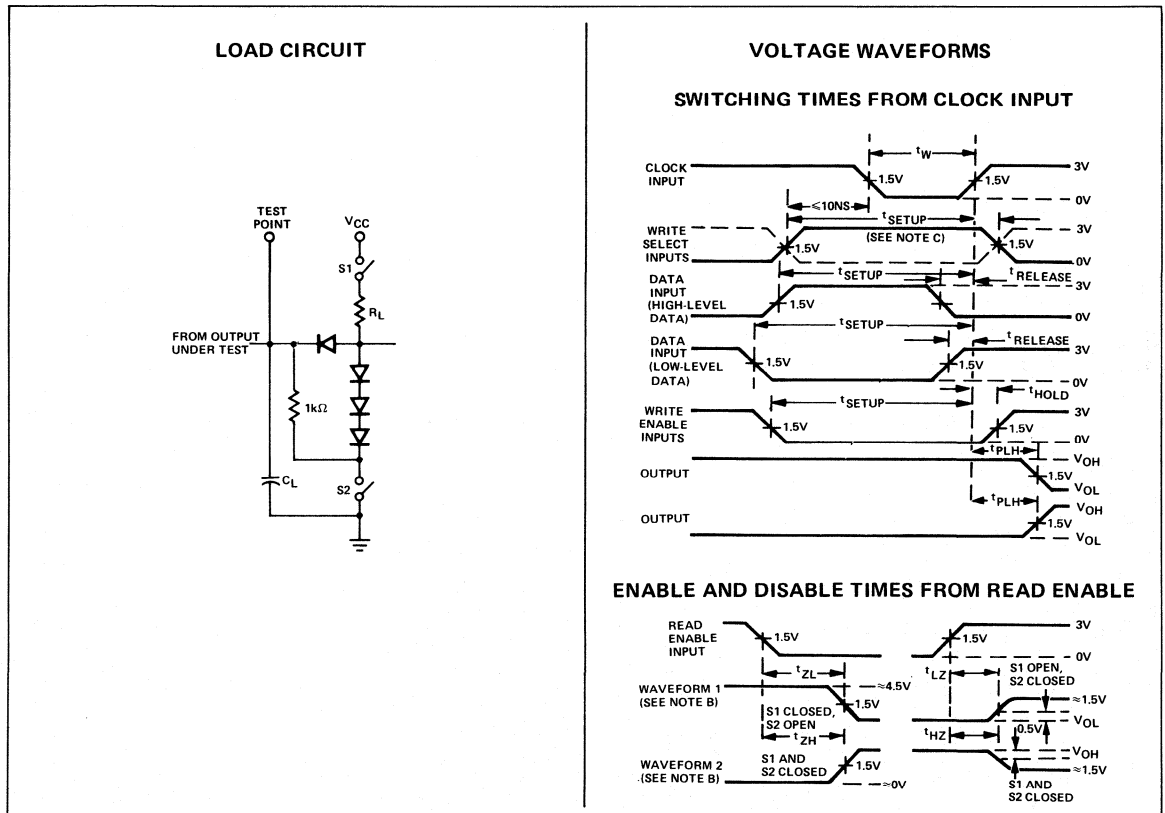
PARAMETER		TEST CONDITIONS <sup>1</sup>	MIN	TYP <sup>2</sup>	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage				-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$				V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -5.2\text{mA}$	2.4			V
$I_{O(\text{off})}$	Off-state (high-impedance state) output current	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 16\text{mA}$			0.4	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_O = 2.4\text{V}$			40	$\mu\text{A}$
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			-40	$\mu\text{A}$
$I_{IL}$	Low-level input current	2W/R0, 2W/R1, 2W/R2,			-1.6	mA
		1GW, 2GW, or clock	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$		-0.8	
		Any other input				
$I_{OS}$	Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX}$	-18		-55	$\text{mA}$
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, \text{All inputs at } 4.5\text{V}$ Outputs open		112	170	$\text{mA}$

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.  
 2. All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .  
 3. No more than one output should be shorted at a time.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum clock frequency		25			MHz
$t_{PLH}$	Propagation delay time, low-to-high-level output from read select			33	45	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output from read select	$C_L = 50pF$		30	45	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output from clock	$R_L = 400\Omega$		35	50	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output from clock	See Figure 1		35	50	ns
$t_{ZH}$	Output enable time to high level			14	30	ns
$t_{ZL}$	Output enable time to low level			16	30	ns
$t_{HZ}$	Output disable time from high level	$C_L = 5pF$ ,		6	20	ns
$t_{LZ}$	Output disable time from low level	See Figure 1		11	20	ns

PARAMETER MEASUREMENT INFORMATION



NOTES

- Input waveforms are supplied by pulse generators having the following characteristics:  $t_r \leq 7 \text{ ns}$ ,  $t_f \leq 7 \text{ ns}$ ,  $PRR = 1 \text{ MHz}$ ,  $Z_{OUT} \approx 50\Omega$ .
- Waveform 1 is for an output with internal conditions such that the output is low except when disabled. Waveform 2 is for an output with internal conditions such that the output is high except when disabled.
- Write select setup time, as specified, will protect data written into previous address.



#### DESCRIPTION

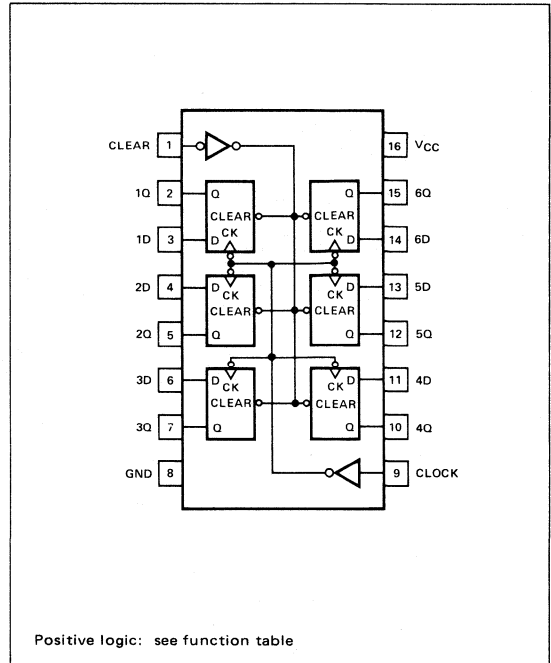
These monolithic, positive-edge-triggered flip-flops utilize TTL circuitry to implement D-type flip-flop logic. The 54/74174 has a direct clear input.

Information at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output.

These circuits are fully compatible for use with most TTL or DTL circuits. A full fanout to 10 normalized Series 54/74 loads is available from each output at low logic levels, and to 20 loads at high logic levels to facilitate connection of unused inputs to used inputs. Maximum clock frequency is typically 35 MHz with a typical power dissipation of 38 milliwatts per flip-flop.

The S54174 characterized for operation over the full military temperature range of -55°C to 125°C. The N74174 is characterized for operation from 0°C to 70°C.

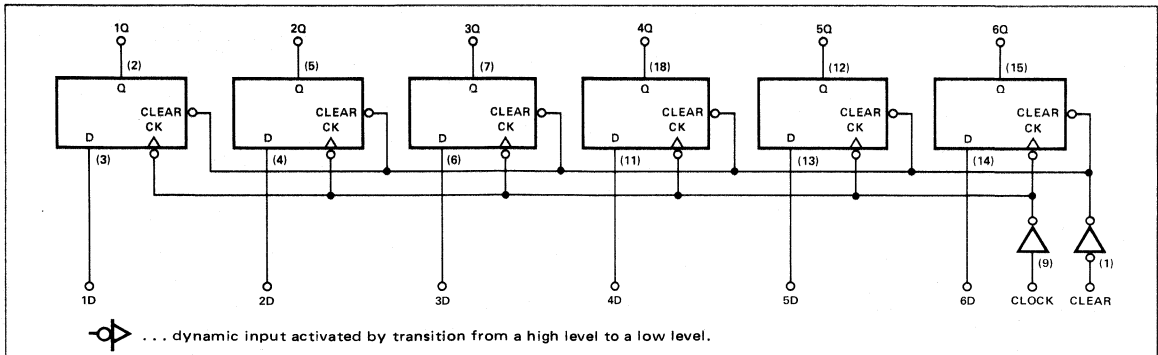
#### PIN CONFIGURATION (Top View)



#### FUNCTION TABLE (Each Flip-Flop)

INPUTS			OUTPUTS	H high level (steady state) L low level (steady state) X irrelevant ↑ transition from low to high level Q <sub>0</sub> the level of Q before the indicated steady state input conditions were established.
Clear	Clock	D	Q	
L	X	X	H	
H	↑	H	H	
H	↑	L	L	
H	L	X	Q <sub>0</sub>	

#### FUNCTIONAL BLOCK DIAGRAM



RECOMMENDED OPERATING CONDITIONS

PARAMETER		S54174			N74174			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	high logic level			20			20	
	low logic level			10			10	
Input clock frequency, $f_{clock}$		0		25	0		25	MHz
Width of clock or clear pulse, $t_w$ (see Figure 1)		20			20			ns
Setup time, $t_{setup}$ (see Figure 1)	data input	20			20			ns
	clear inactive-state	25			25			ns
Data hold time, $t_{hold}$ (see Figure 1)		0			0			ns
Operating free-air temperature, $T_A$		-55		125	0		70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$			-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -800\mu\text{A}$	2.4			V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 16 \text{ mA}$			0.4	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			40	μA
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$			-1.6	mA
$I_{OS}$	Short-circuit output current §	$V_{CC} = \text{MAX}$ SN54174, SN54175	-20		-57	mA
		SN74174, SN74175	-18		-57	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ , See Note 1		45	65	mA
		SN54174, SN74174		30	45	
SN54175, SN74175						

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

‡ All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

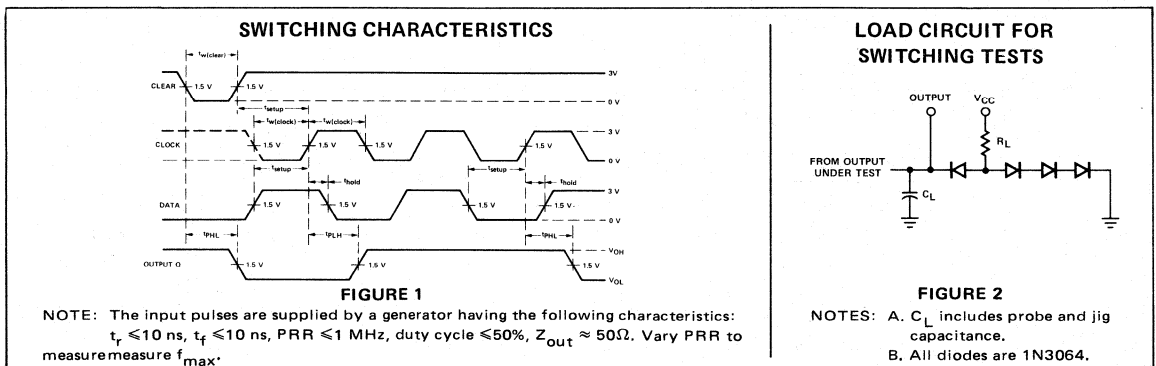
§ Not more than one output should be shorted at a time.

NOTE 1: With all outputs open and 4.5V applied to all data and clear inputs,  $I_{CC}$  is measured after a momentary ground, then 4.5V, is applied to clock.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum input clock frequency		25	35		MHz
$t_{PHL}$	Propagation delay time, high-to-low-level output from clear	$C_L = 15 \text{ pF}, R_L = 400 \Omega$		23	35	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output from clock	See Figures 1 and 2		20	30	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output from clock			21	30	ns

PARAMETER MEASUREMENT INFORMATION



S54175—B,F,W • N74175—B,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These monolithic, positive-edge-triggered flip-flops utilize TTL circuits to implement the D-type flip-flop logic. Information at input D is transferred to the Q output on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level of the clock pulse and is not directly related to the transition time of the positive-going pulse. When the clock input is at either the high or low level, the D-input signal has no effect.

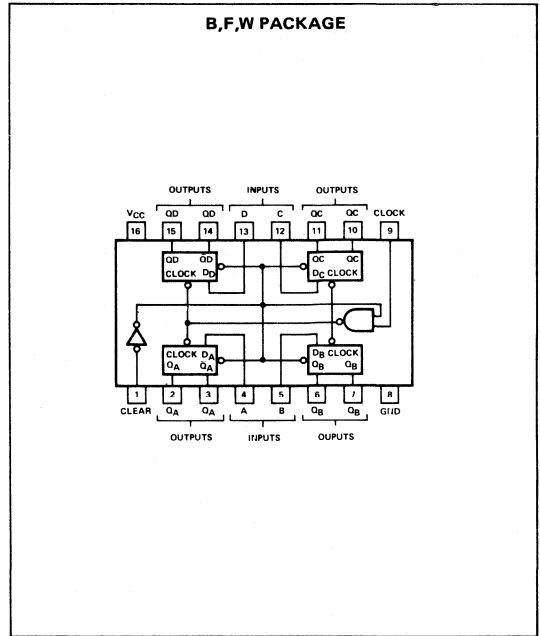
These circuits are fully compatible for use with most TTL or DTL circuits. A full fan-out to 10 low logic-level loads and 20 high-level loads is available from each of the outputs. This simplifies system design by allowing unused inputs to be tied to driven inputs. Maximum clock frequency is typically 25 megahertz, with a typical power dissipation of 38 milliwatts per flip-flop.

### TRUTH TABLE

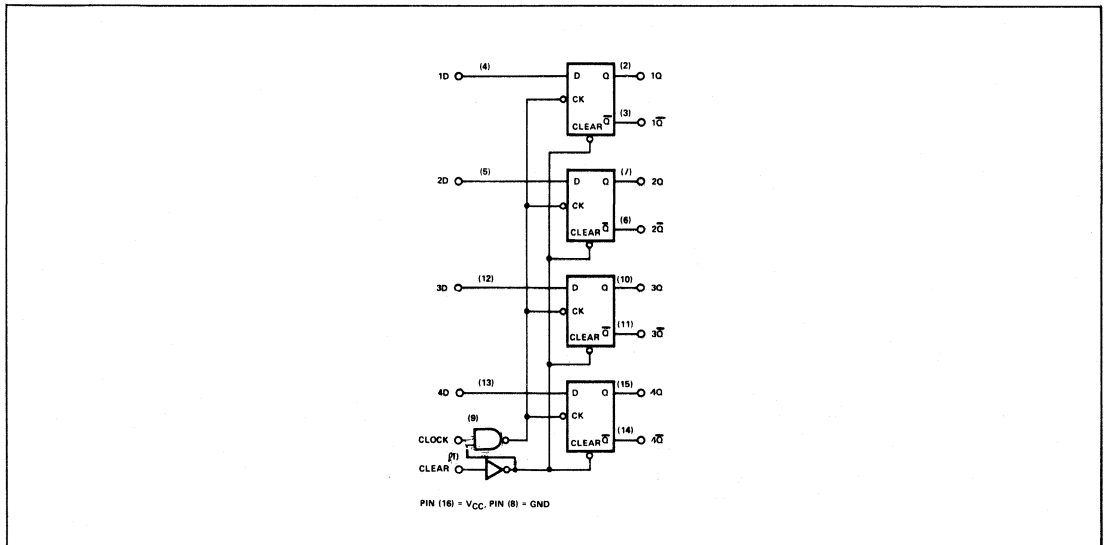
INPUT	OUTPUT
$t_n$	$t_n + 1$
D	Q
H	H
L	L

$t_n$  = Bit time before clock pulse transition.  
 $t_n + 1$  = Bit time after clock pulse transition.

### PIN CONFIGURATION



### LOGIC DIAGRAM



# SIGNETICS QUADRUPLE D-TYPE EDGE-TRIGGERED FLIP-FLOPS ■ S54175, N74175

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	54175			74175			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High Logic Level			20			
	Low Logic Level			10			
Input clock frequency, $f_{clock}$	0		25	0		25	MHz
Width of clock or clear pulse, $t_{W}$ (See Figure 1)	20			20			ns
Data setup time, $t_{setup}$ (See Figure 1)	20			20			ns
Hold time $t_{hold}$ (See Figure 1)	0			0			ns
Operating free-air temperature, $T_A$	-55	25	125	0	25	70	°C
Clear release setup, $t_{release}$ (See Figure 1)	25			25			ns

## ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS†	54175			74175			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage	$V_{CC} = MAX, I_I = -12 \text{ mA}$			-1.5			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = MIN, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -800 \mu\text{A}$	2.4			2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = MIN, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 16 \text{ mA}$			0.4			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = MAX, V_I = 5.5 \text{ V}$			1			1	mA
$I_{IH}$ High-level input current	$V_{CC} = MAX, V_I = 2.4 \text{ V}$			40			40	$\mu\text{A}$
$I_{IL}$ Low-level input current	$V_{CC} = MAX, V_I = 0.4 \text{ V}$			-1.6			-1.6	mA
$I_{OS}$ Short-circuit output current §	$V_{CC} = MAX$	-20		-57	-18		-57	mA
$I_{CC}$ Supply current	$V_{CC} = MAX$							
	Note 1		30	45		30	45	mA

§ Not more than one output should be started at a time.

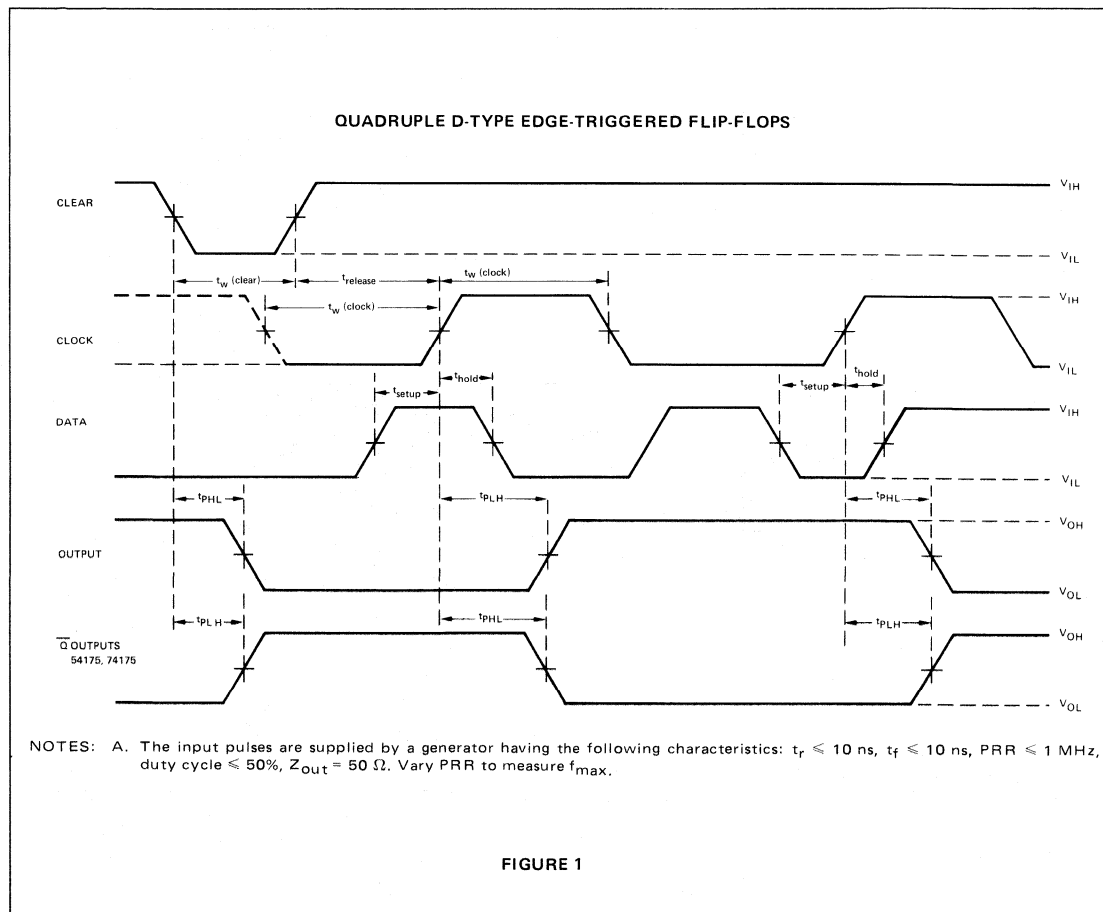
NOTE 1: With all outputs open and 4.5V applied to all data and clear inputs,  $I_{CC}$  is measured after a momentary ground, then 4.5V, is applied to clock.

# SIGNETICS QUADRUPLE D-TYPE EDGE-TRIGGERED FLIP-FLOPS ■ S54175, N74175

SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{ C}$ ,  $N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\max}$	Maximum input clock frequency	25	35		MHz
$t_{\text{PHL}}$	Propagation delay time, high-to-low-level output Q from clear	$C_L = 15\text{ pF}$ $R_L = 400$	23	35	ns
$t_{\text{PLH}}$	Propagation delay time low-to-high-level output Q from clear (54175, 74175)		16	25	ns
$t_{\text{PHL}}$	Propagation delay time, high-to-low-level output from clock		21	30	ns
$t_{\text{PLH}}$	Propagation delay time, low-to-high-level output from clock		20	30	ns

## SWITCHING TIMES



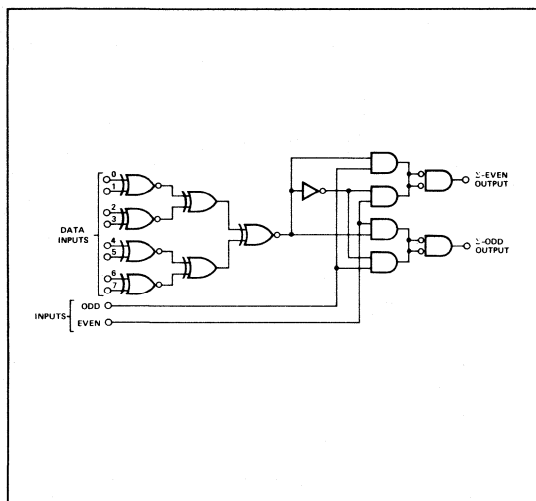
S54180—A,F,W • N74180—A,F

DIGITAL 54/74 TTL SERIES

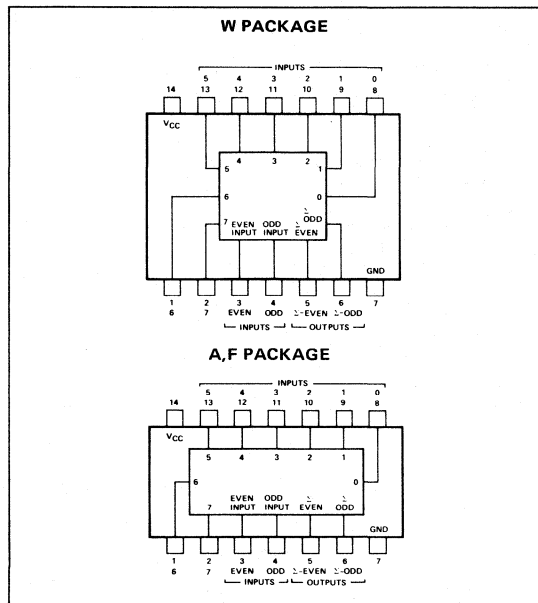
### DESCRIPTION

The 54/74180 8-Bit Odd/Even Parity Generator/Checker is a TTL monolithic array featuring gating logic arranged to generate or check odd or even parity.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

INPUTS			OUTPUTS	
$\Sigma$ OF 1's AT 0 THRU 7	EVEN	ODD	$\Sigma$ EVEN	$\Sigma$ ODD
EVEN	1	0	1	0
ODD	1	0	0	1
EVEN	0	1	0	1
ODD	0	1	1	0
X	1	1	0	0
X	0	0	1	1

X = Irrelevant

### RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$	S54180	4.5	5	5.5	V
	N74180	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: Logical 0 Logical 1				10	V
				20	V

# SIGNETICS 8-BIT ODD/EVEN PARITY GENERATOR/CHECKER ■ S54180, N74180

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V,$ $V_{in(0)} = 0.8V, I_{load} = -800 \mu A$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}, V_{in(1)} = 2V,$ $V_{in(0)} = 0.8V, I_{sink} = 16mA$			0.4	V
$I_{in(1)}$	Logical 1 level input current at each data input	$V_{CC} = \text{MAX}, V_{in} = 2.4V$ $V_{CC} = \text{MAX}, V_{in} = 5.5V$			40	$\mu A$
$I_{in(0)}$	Logical 0 level input current at each data input	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			1	mA
$I_{in(1)}$	Logical 1 level input current at even or odd input	$V_{CC} = \text{MAX}, V_{in} = 2.4V$ $V_{CC} = \text{MAX}, V_{in} = 5.5V$			80	$\mu A$
$I_{in(0)}$	Logical 0 level input current at even or odd input	$V_{CC} = \text{MAX}, V_{in} = 0.4V$			1	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX}$				
		S54180	-20		-55	mA
		N74180	-18		-55	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$				
		S54180		34	49	mA
		N74180		34	56	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd1}$	Data	$\Sigma$ Even	$C_L = 15pF,$	$R_L = 400 \Omega$		40	60	ns
$t_{pd0}$	Data	$\Sigma$ Even	$C_L = 15pF,$	$R_L = 400 \Omega$		25	38	ns
$t_{pd1}$	Data	$\Sigma$ Odd	$C_L = 15pF,$	$R_L = 400 \Omega$		32	48	ns
$t_{pd0}$	Data	$\Sigma$ Odd	$C_L = 15pF,$	$R_L = 400 \Omega$		45	68	ns
$t_{pd1}$	Data	$\Sigma$ Even	$C_L = 15pF,$	$R_L = 400 \Omega$		32	48	ns
$t_{pd0}$	Data	$\Sigma$ Even	$C_L = 15pF,$	$R_L = 400 \Omega$		45	68	ns
$t_{pd1}$	Data	$\Sigma$ Odd	$C_L = 15pF,$	$R_L = 400 \Omega$		40	60	ns
$t_{pd0}$	Data	$\Sigma$ Odd	$C_L = 15pF,$	$R_L = 400 \Omega$		25	38	ns
$t_{pd1}$	Even or Odd	$\Sigma$ Even or $\Sigma$ Odd	$C_L = 15pF,$	$R_L = 400 \Omega$		13	20	ns
$t_{pd0}$	Even or Odd	$\Sigma$ Even or $\Sigma$ Odd	$C_L = 15pF,$	$R_L = 400 \Omega$		7	10	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions of the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

#### DESCRIPTION

The 54181 and 74181 are high-speed arithmetic logic units (ALU)/function generators which have a complexity of 75 equivalent gates on a monolithic chip. This circuit performs 16 binary arithmetic operations on two 4-bit words as shown in the function table. These operations are selected by the four function-select lines (S0, S1, S2, S3) and include addition, subtraction, decrement, and straight transfer. When performing arithmetic manipulations, the internal carries must be enabled by applying a low-level voltage to the mode control input (M). A full carry look-ahead scheme is made available in the 54181/74181 for fast, simultaneous carry generation with a group carry propagate (P) and carry generate (G) for the 4 bits in the package. When used in conjunction with the 54182 or 74182 full carry look-ahead circuits, high-speed arithmetic operations can be performed. For example, the typical addition time for the 54181/74181 is 24 nanoseconds for 4 bits. When expanding to 16-bit addition with the 54182/74182, only 13 nanoseconds, further delay is added so that the total addition time is 35 nanoseconds, or 2.2 nanoseconds per bit. One 54182/74182 is needed for every 16 bits (four 54181/74181 circuits).

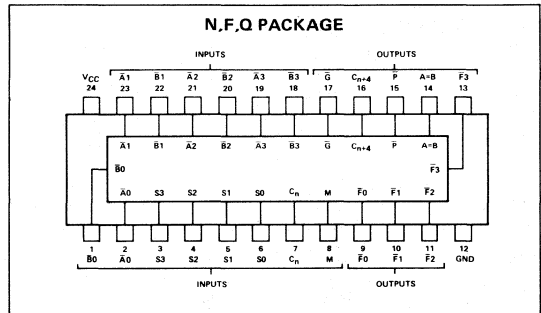
If high speed is not of importance, a ripple-carry input ( $C_n$ ) and a ripple-carry output ( $C_{n+4}$ ) are available. However, the ripple-carry delay has also been minimized so that arithmetic manipulations for small word lengths can be performed without external circuitry. The typical delay for the ripple carry is 12 nanoseconds for four bits, addition of two 8-bit words is accomplished typically in 36 nanoseconds when employing the ripple carry.

The 54181/74181 will accommodate active-high or active-low data if the pin-designations are reinterpreted as follows:

These circuits have been designed to not only incorporate all of the designer's requirements for arithmetic operations, but also to provide 16 possible functions of two Boolean variables without the use of external circuitry. These logic functions are selected by use of the four function-select inputs (S0, S1, S2, S3) with the mode control input (M) at a high level to disable the internal carry. The 16 logic functions are detailed in the function table and include exclusive-OR, NAND, AND, NOR and OR functions.

The 54181/74181 is designed with a Darlington output configuration (54H/74H type) to reduce the high-logic-level output impedance and thereby improve the turn-off propagation delay time. All outputs are rated at a normalized fan-out of ten at the low logic level and increased to a fan-out of 20 at the high logic level. The increased high-logic-level fan-out allows the system designer more freedom in tying unused inputs to driven inputs.

#### PIN CONFIGURATION



PIN NUMBER	2	1	23	22	21	20	19	18	9	10	11	13	7	16	15	17
Active-high data	A <sub>0</sub>	B <sub>0</sub>	A <sub>1</sub>	B <sub>1</sub>	A <sub>2</sub>	B <sub>2</sub>	A <sub>3</sub>	B <sub>3</sub>	F <sub>0</sub>	F <sub>1</sub>	F <sub>2</sub>	F <sub>3</sub>	$\overline{C_n}$	$\overline{C_{n+4}}$	X	Y
Active-low data	$\overline{A_0}$	$\overline{B_0}$	$\overline{A_1}$	$\overline{B_1}$	$\overline{A_2}$	$\overline{B_2}$	$\overline{A_3}$	$\overline{B_3}$	$\overline{F_0}$	$\overline{F_1}$	$\overline{F_2}$	$\overline{F_3}$	C <sub>n</sub>	C <sub>n+4</sub>	$\overline{P}$	$\overline{G}$

Subtraction is accomplished by 1's complement addition where the 1's complement of the subtrahend is generated internally. The resultant output is  $A-B-1$  which requires an end-around or forced carry to provide  $A-B$ .

The 54181/74181 can also be utilized as a comparator. The  $A=B$  output is internally decoded from the function outputs (F0, F1, F2, F3) so that when two words of equal magnitude are applied at the A and B inputs, it will assume a high-level state to indicate equality ( $A=B$ ). The 54181/74181 should be in the subtract mode when performing this comparison. The  $A=B$  output is open-collector so that it can be wire-AND connected to give a comparison for more than four bits. The carry output ( $C_{n+4}$ ) can also be used to supply relative magnitude information. Again, the ALU should be placed in the subtract mode by placing the control lines at LHHL.

The 54181 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 74181 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### TRUTH TABLE FOR COMPARATOR APPLICATION

	Input C <sub>n</sub>	Output C <sub>n+4</sub>	Indicates
Active-high Data	H	H	A < B
	L	H	A < B
	H	L	A > B
	L	L	A > B
Active-low Data	L	L	A < B
	H	L	A < B
	L	H	A > B
	H	H	A > B

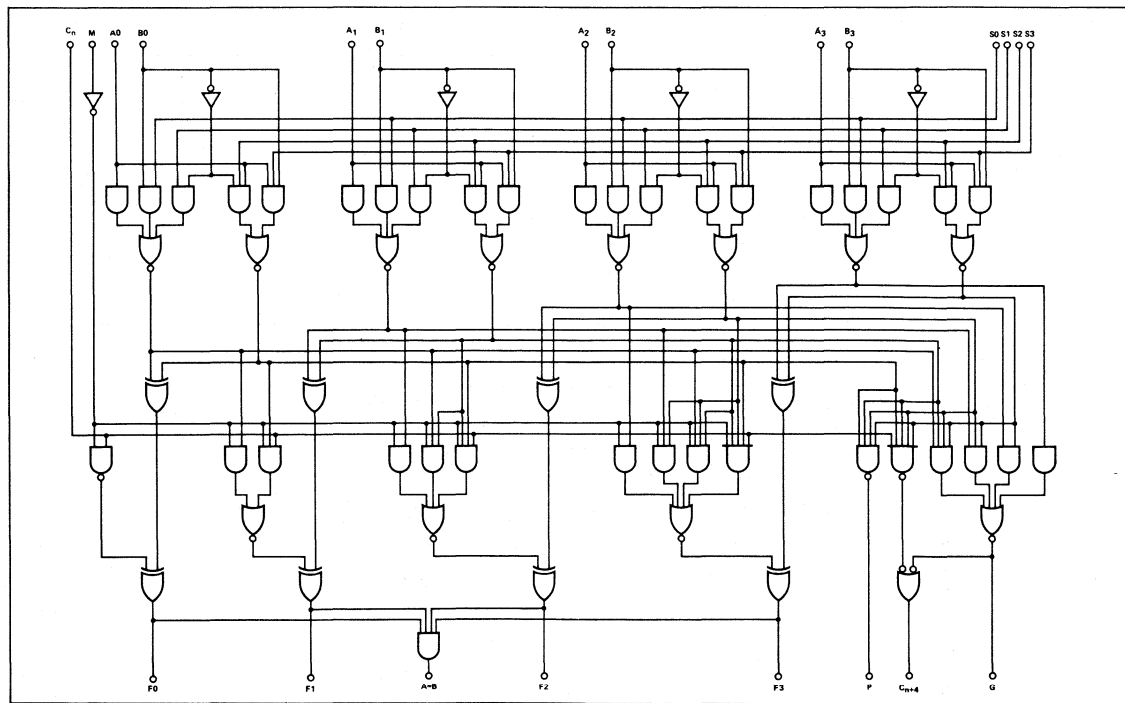


FUNCTION TABLES

SELECTION S <sub>3</sub> S <sub>2</sub> S <sub>1</sub> S <sub>0</sub>	ACTIVE-HIGH DATA		
	M = H LOGIC FUNCTIONS	M = L: ARITHMETIC OPERATIONS	
		C <sub>n</sub> = 0 C <sub>n</sub> = 1 = H	C <sub>n</sub> = 1 C <sub>n</sub> = 0 = L
L L L L	F = $\bar{A}$	F = A	F = A PLUS 1
L L L L	F = $\bar{A} + \bar{B}$	F = A + B	F = (A + B) PLUS 1
L L H L	F = $\bar{A}B$	F = A + $\bar{B}$	F = (A + $\bar{B}$ ) PLUS 1
L L H H	F = 0	F = MINUS 1 (2's COMPL)	F = ZERO
L H L L	F = $\bar{A}B$	F = A PLUS $\bar{A}\bar{B}$	F = A PLUS $\bar{A}\bar{B}$ PLUS 1
L H L H	F = $\bar{B}$	F = (A + B) PLUS $\bar{A}\bar{B}$	F = (A + B) PLUS $\bar{A}\bar{B}$ PLUS 1
L H H L	F = $A \odot B$	F = A MINUS B MINUS 1	F = A MINUS B
L H H H	F = $\bar{A}\bar{B}$	F = $\bar{A}\bar{B}$ MINUS 1	F = $\bar{A}\bar{B}$
H L L L	F = $\bar{A} + B$	F = A PLUS AB	F = A PLUS AB PLUS 1
H L L H	F = $\bar{A} \odot B$	F = A PLUS B	F = A PLUS B PLUS 1
H L H L	F = B	F = (A + $\bar{B}$ ) PLUS AB	F = (A + $\bar{B}$ ) PLUS AB PLUS 1
H L H H	F = AB	F = AB MINUS 1	F = AB
H H L L	F = 1	F = A PLUS A	F = A PLUS A PLUS 1
H H L H	F = $A + \bar{B}$	F = (A + $\bar{B}$ ) PLUS A	F = (A + $\bar{B}$ ) PLUS A PLUS 1
H H H L	F = A + B	F = (A + $\bar{B}$ ) PLUS A	F = (A + $\bar{B}$ ) PLUS A PLUS 1
H H H H	F = A	F = A MINUS 1	F = A

SELECTION S <sub>3</sub> S <sub>2</sub> S <sub>1</sub> S <sub>0</sub>	ACTIVE-LOW DATA		
	M = H LOGIC FUNCTIONS	M = L: ARITHMETIC OPERATIONS	
		C <sub>n</sub> = 0 C <sub>n</sub> = 0 = L	C <sub>n</sub> = 1 C <sub>n</sub> = 1 = H
L L L L	F = $\bar{A}$	F = A MINUS 1	F = A
L L L H	F = $\bar{A}\bar{B}$	F = AB MINUS 1	F = AB
L L H L	F = $\bar{A} + B$	F = $\bar{A}\bar{B}$ MINUS 1	F = $\bar{A}\bar{B}$
L L H H	F = 1	F = MINUS 1 (2's COMP)	F = ZERO
L H L L	F = $\bar{A} + B$	F = A PLUS (A + $\bar{B}$ )	F = A PLUS (A + $\bar{B}$ ) PLUS 1
L H L H	F = $\bar{B}$	F = AB PLUS (A + $\bar{B}$ )	F = AB PLUS (A + $\bar{B}$ ) PLUS 1
L H H L	F = $A \odot B$	F = A MINUS B MINUS 1	F = A MINUS B
L H H H	F = $\bar{A} + \bar{B}$	F = A + $\bar{B}$	F = (A + $\bar{B}$ ) PLUS 1
H L L L	F = $\bar{A}\bar{B}$	F = A PLUS (A + B)	F = A PLUS (A + B) PLUS 1
H L L H	F = $A \odot B$	F = A PLUS B	F = A PLUS B PLUS 1
H L H L	F = B	F = $\bar{A}\bar{B}$ PLUS (A + B)	F = $\bar{A}\bar{B}$ PLUS (A + B) PLUS 1
H L H H	F = A + B	F = A + B	F = (A + B) PLUS 1
H H L L	F = 0	F = A PLUS A	F = A PLUS A PLUS 1
H H L H	F = $\bar{A}\bar{B}$	F = AB PLUS A	F = AB PLUS A PLUS 1
H H H L	F = AB	F = $\bar{A}\bar{B}$ PLUS A	F = $\bar{A}\bar{B}$ PLUS A PLUS 1
H H H H	F = A	F = A	F = A PLUS 1

LOGIC DIAGRAM



RECOMMENDED OPERATING CHARACTERISTICS

PARAMETER	S54181			N74181			UNIT	
	MIN	NOM	MAX	MIN	NOM	MAX		
Supply Voltage V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V	
Normalized Fan-Out from each Output, N:	High logic level						20	°C
	Low logic level						10	
Operating Free-Air Temperature Range, T <sub>A</sub>	-55	25	125	0	25	70		

# SIGNETICS HIGH-SPEED ARITHMETIC LOGIC ■ S54181, N74181

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT	
V <sub>IH</sub> High-level input voltage		2			V	
V <sub>IL</sub> Low-level input voltage				0.8	V	
V <sub>OH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OH</sub> = -800μA	2.4			V	
V <sub>OL</sub> Low-level output voltage any output except A=B	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OL</sub> = 16mA			0.4	V	
I <sub>OH</sub> High-level output current A=B only	V <sub>CC</sub> = MIN, V <sub>IN</sub> = 2V, V <sub>IL</sub> = 0.80, V <sub>OH</sub> = 5.5V			250	μA	
I <sub>IH</sub> High-level input current (mode input)				40	μA	
I <sub>IH</sub> High-level input current (any A or B input)				120	μA	
I <sub>IH</sub> High-level input current (any S input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4V			160	μA	
I <sub>IH</sub> High-level input current (carry input)				200	μA	
I <sub>IH</sub> High-level input current (any input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1	mA	
I <sub>IL</sub> Low-level input current (mode input)				-1.6	mA	
I <sub>IL</sub> Low-level input current (any A or B input)				-4.8	mA	
I <sub>IL</sub> Low-level input current (any S input)	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4V			-6.4	mA	
I <sub>IL</sub> Low-level input current (carry input)				-8	mA	
I <sub>OS</sub> Short-circuit output current §	V <sub>CC</sub> = MAX	S54181 N74181		-20 -18	-55 -57	mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX	S54181 N74181	88	127	mA	
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX	S54181 N74181	94	135	mA	
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX	S54181 N74181	94	150	mA	

## SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C, N = 10 (C<sub>L</sub> = 15pF, R<sub>L</sub> = 400Ω)

PARAMETER†	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>					12	18	ns
t <sub>PHL</sub>	C <sub>n</sub>	C <sub>n+4</sub>			13	19	
t <sub>PLH</sub>			M = 0V		13	19	ns
t <sub>PHL</sub>	C <sub>n</sub>	Any F	(SUM or DIFF mode)		12	18	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 4.5V,		13	19	ns
t <sub>PHL</sub>	Any A or B	G	S <sub>1</sub> = S <sub>2</sub> = 0V (SUM mode)		13	19	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 0V,		17	25	ns
t <sub>PHL</sub>	Any A or B	G	S <sub>1</sub> = S <sub>2</sub> = 4.5V (DIFF mode)		17	25	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 4.5V,		13	19	ns
t <sub>PHL</sub>	Any A or B	P	S <sub>1</sub> = S <sub>2</sub> = 0V (SUM mode)		17	25	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 0V,		17	25	ns
t <sub>PHL</sub>	Any A or B	P	S <sub>1</sub> = S <sub>2</sub> = 4.5V (DIFF mode)		17	25	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 4.5V,		28	42	ns
t <sub>PHL</sub>	Any A or B	Any F	S <sub>1</sub> = S <sub>2</sub> = 0V (SUM mode)		21	32	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 0V,		32	48	ns
t <sub>PHL</sub>	Any A or B	Any F	S <sub>1</sub> = S <sub>2</sub> = 4.5V (DIFF mode)		23	34	
t <sub>PLH</sub>			M = 4.5V (logic mode)		32	48	ns
t <sub>PHL</sub>	Any A or B	Any F			23	34	
t <sub>PLH</sub>			M = 0V, S <sub>0</sub> = S <sub>3</sub> = 0V,		35	50	ns
t <sub>PHL</sub>	Any A or B	A = B	S <sub>1</sub> = S <sub>2</sub> = 4.5V (DIFF mode)		32	48	

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.

† t<sub>PLH</sub> = propagation delay time, low-to-high-level output    t<sub>PHL</sub> = propagation on delay time, high-to-low-level output

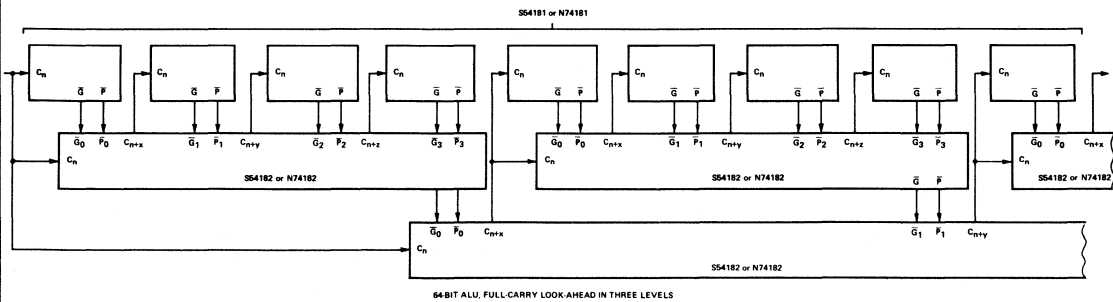
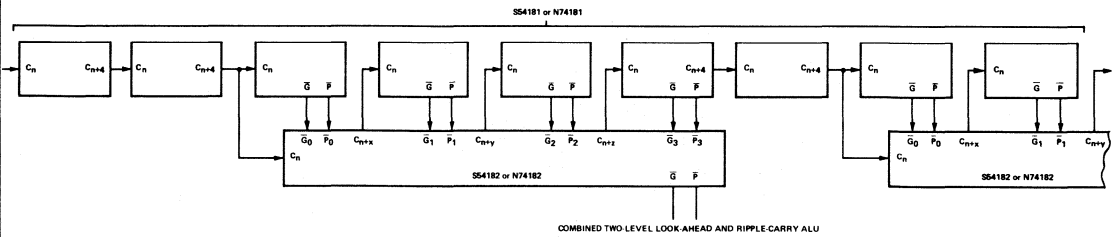
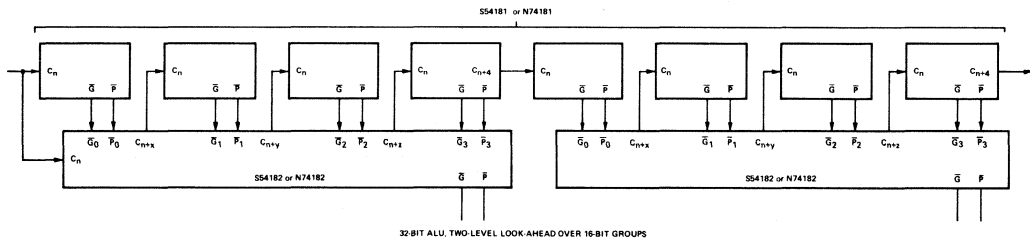
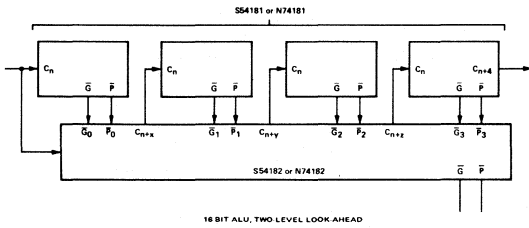
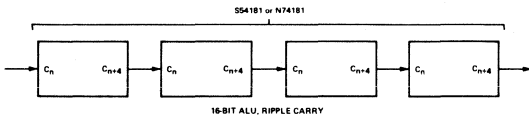
§ Not more than one output should be shorted at a time

TYPICAL APPLICATION DATA

Typical addition times for various configurations are given in the table below. Subtraction times are in the same range as summation times.

TYPICAL ADDITION TIMES

NO. OF BITS	TOTAL ADDITION TIME (ns)	ADD TIME PER BIT (ns)	PACKAGE COUNT	
			S54181/ N74181	S54182 N74182
4	24	6.0	1	
8	36	4.5	2	
12	48	4.0	3	
12	36	3.0	3	1
16	60	3.8	4	
16	36	2.2	4	1
32	120	3.8	8	
32	96	3.0	8	1
32	72	2.2	8	2
32	60	1.9	8	3
48	165	3.4	12	
48	148	3.1	12	1
48	132	2.7	12	2
48	108	2.2	12	3
48	60	1.25	12	4
64	220	3.5	16	
64	192	3.0	16	2
64	172	2.7	16	3
64	144	2.2	16	4
64	60	0.94	16	5



S54182-B,F,W • N74182-B,F

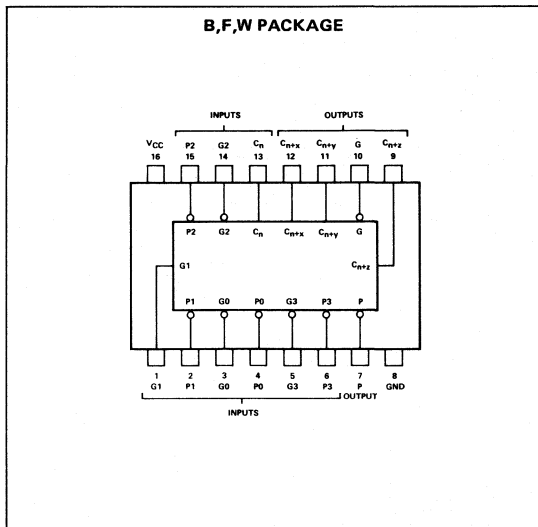
DIGITAL 54/74 TTL SERIES

### DESCRIPTION

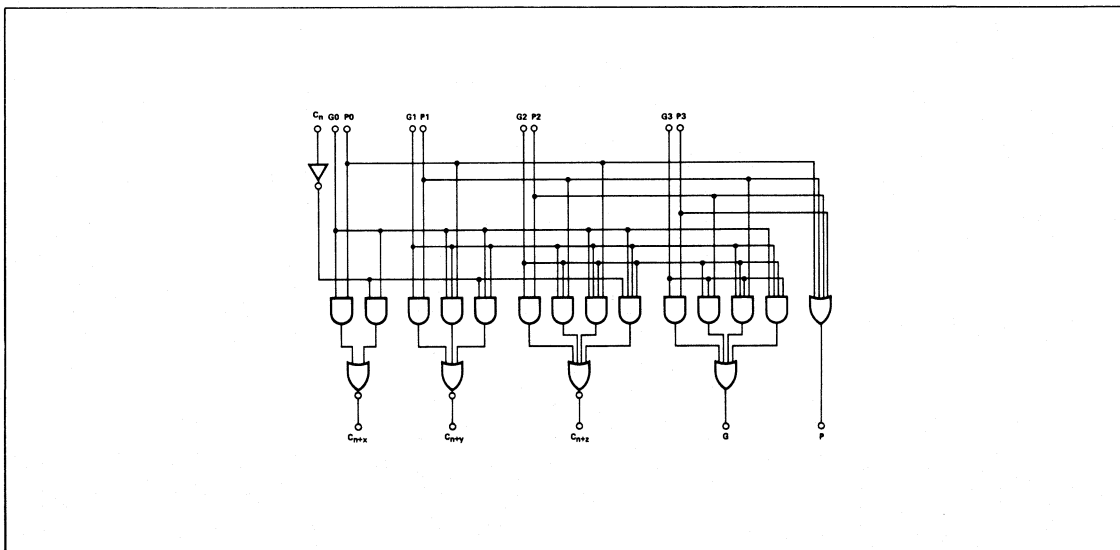
The S54182, N74182 is a high-speed, look-ahead carry generator capable of anticipating a carry across four binary adders or group of adders. It is cascadable to perform full look-ahead across n-bit adders, with only 13 nanoseconds delay for each level of look-ahead. Carry, generate-carry, and propagate-carry functions are provided as enumerated in the pin designation table above.

The S54182 or N74182, when used in conjunction with the S54181 or N74181 arithmetic logic unit (ALU), provides full high-speed carry look-ahead capability for up to n-bit words. Each S54182/N74182 generates the look-ahead (anticipated carry) across a group of four ALUs and, in addition, other carry look-ahead circuits may be employed to anticipate carry across sections of four look-ahead packages up to n-bits. Applications data for the S54181/N74181 illustrates cascading of S54182/N74182 circuits to perform multi-level look-ahead.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



### RECOMMENDED OPERATING CONDITIONS

	S54182			N74182			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: High logic level			20			20	
Low logic level			10			10	
Operating Free-Air Temperature Range, $T_A$	-55	25	125	0	25	70	$^{\circ}C$



#### DESCRIPTION

The 54190, 54191, 74190, and 74191 are synchronous, reversible up/down counters having a complexity of 58 equivalent gates. The 54191 and 74191 are 4-bit binary counters and the 54190 and 74190 are BCD counters. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincident with each other when so instructed by the steering logic. This mode of operation will eliminate the output counting spikes which are normally associated with asynchronous (ripple clock) counters.

The outputs of the four master-slave flip-flops are triggered on a low-to-high-level transition of the clock input if the enable input is low. A high at the enable input inhibits counting. Level changes at the enable input should be made only when the clock input is high. The direction of the count is determined by the state of the down/up input. When low, the counter counts up and when high, it counts down.

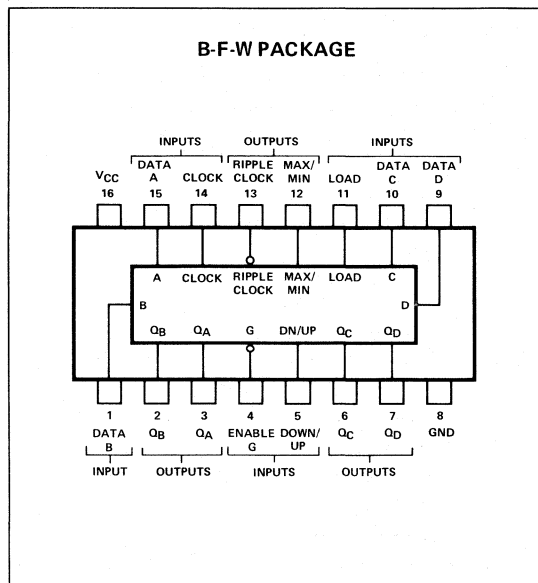
These counters are fully programmable; that is, the outputs may be preset to any state by placing a low on the load input and entering the desired data at the data inputs. The output will change to agree with the data inputs independently of the state of the clock input. This feature allows the counters to be used as modulo-N dividers by simply modifying the count length with the preset inputs.

Input buffers have been used to lower the fan-in requirement to only one normalized Series 54/74 load at all inputs except enable. This is important when the output of the driving circuitry is somewhat limited.

Two outputs have been made available to perform the cascading function: ripple clock and maximum/minimum count. The latter output produces a high-level output pulse with a duration approximately equal to one complete cycle of the clock when the counter overflows or underflows. The ripple clock output produces a low-level output pulse equal in width to the low-level portion of the clock input when an overflow or underflow condition exists. The counters can be easily cascaded by feeding the ripple clock output to the enable input of the succeeding counter if parallel clocking is used, or to the clock input if parallel enabling is used. The maximum/minimum count output can be used to accomplish look-ahead for high-speed operation.

Power dissipation is typically 325 milliwatts for either the decade or binary version. Maximum input clock frequency is typically 25 megahertz and is guaranteed to be at least 20 megahertz.

#### PIN CONFIGURATION



asynchronous inputs: Low input to load sets  $Q_A = A$ ,  $Q_B = B$ ,  $Q_C = C$ , and  $Q_D = D$

† Pin assignments for these circuits are the same for all packages.

The 54190 and 54191 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 74190 and 74191 are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range  
(unless otherwise noted)

Supply Voltage, $V_{CC}$ (See Note 1)	7 V
Input Voltage (See Note 1)	5.5 V
Operating Free-Air Temperature Range:	
54190, 54191	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
74190, 74191	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

#### NOTES:

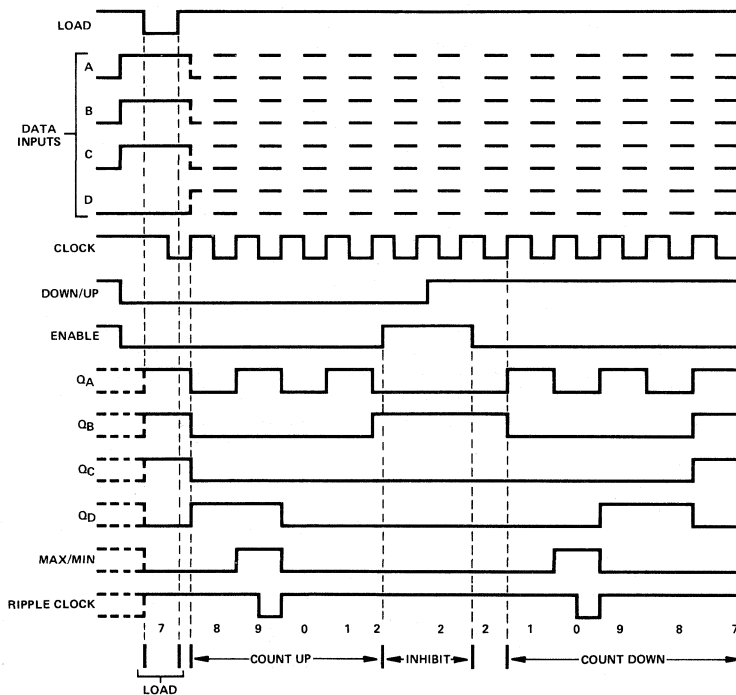
1. Voltage values are with respect to network ground terminal.

DECADE COUNTERS, 54190, 74190

**TYPICAL LOAD, COUNT, AND INHIBIT SEQUENCES**

Illustrated below is the following sequence:

1. Load (preset) to BCD seven.
2. Count up to eight, nine (maximum), zero, one, and two.
3. Inhibit.
4. Count down to one, zero (minimum), nine, eight, and seven.



RECOMMENDED OPERATING CONDITIONS

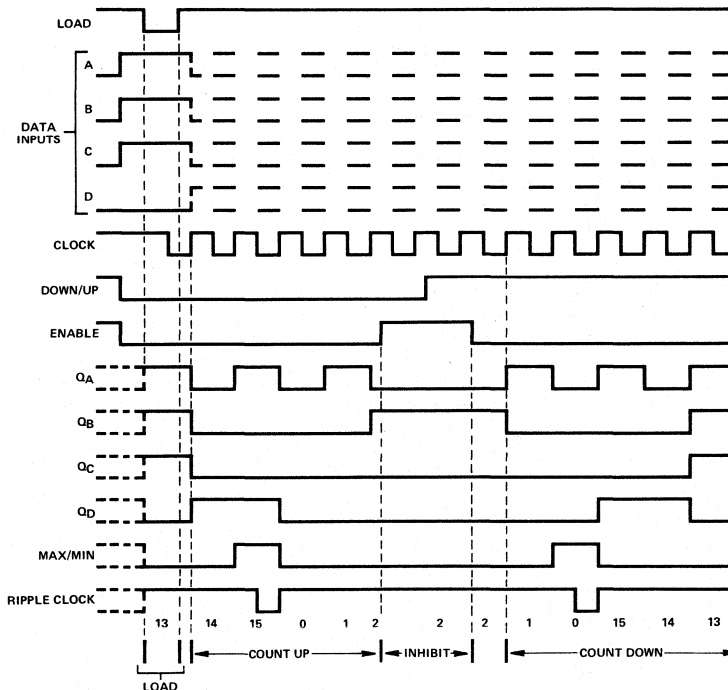
PARAMETER	54190, 54191			74190, 74191			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20			20	
	Low logic level		10			10	
Input clock frequency, $f_{clock}$	0		20	0		20	MHz
Width of clock input pulse, $t_w(\text{clock})$	25		25				ns
Width of load input pulse, $t_w(\text{load})$	35			35			ns
Data setup time, $t_{setup}$ (See Figures 1 and 2)	20		20				ns
Data hold time, $t_{hold}$	0			0			ns
Operating free-air temperature, $T_A$	-55	25	125	0	25	70	°C

BINARY COUNTERS, 54191, 74191

TYPICAL LOAD, COUNT, AND INHIBIT SEQUENCES

Illustrated below is the following sequence:

1. Load (preset) to binary thirteen.
2. Count up to fourteen, fifteen (maximum), zero, one, and two.
3. Inhibit.
4. Count down to one, zero (minimum), fifteen, fourteen, and thirteen.





**ELECTRICAL CHARACTERISTICS OVER OPERATING FREE-AIR TEMPERATURE RANGE**

(Unless Otherwise Noted)

PARAMETER	TEST CONDITIONS <sup>1</sup>	54190, 54191			74190, 74191			UNIT
		MIN	TYP <sup>2</sup>	MAX	MIN	TYP <sup>3</sup>	MAX	
V <sub>IH</sub> High-level input voltage	V <sub>CC</sub> = MIN	2			2			V
V <sub>IL</sub> Low-level input voltage	V <sub>CC</sub> = MIN			0.8			0.8	V
V <sub>I</sub> Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12mA			-1.5			-1.5	V
V <sub>OH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OH</sub> = -800μA	2.4			2.4			V
V <sub>OL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OL</sub> = 16mA			0.4			0.4	V
I <sub>I</sub> High-level input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1			1	mA
I <sub>IH</sub> High-level input current at any input except enable	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4V			40			40	μA
I <sub>IH</sub> High-level input current at enable input				120			120	μA
I <sub>IL</sub> Low-level input current at any input except enable	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4V			-1.6			-1.6	mA
I <sub>IL</sub> Low-level input current at enable input				-4.8			-4.8	mA
I <sub>OS</sub> Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX	-20		-65	-18		-65	mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX, See Note 2		65	105		65	105	mA

1. For conditions shown as MAX or MIN, use appropriate value specified under recommended operating conditions for the applicable device type.

2. All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C

3. Not more than one output should be shorted at a time.

NOTE 2: I<sub>CC</sub> is measured with all inputs grounded and all outputs open.

**SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C, N = 10**

PARAMETER <sup>1</sup>	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f <sub>max</sub>				20	25		MHz
t <sub>PLH</sub>	Load	Q <sub>A</sub> , Q <sub>B</sub> , Q <sub>C</sub> , Q <sub>D</sub>	C <sub>L</sub> = 15pF, R <sub>L</sub> = 400Ω, See Figure 1 and Figures 3 thru 7		22	33	ns
t <sub>PHL</sub>					33	50	
t <sub>PLH</sub>	Data A, B, C, C	Q <sub>A</sub> , Q <sub>B</sub> , Q <sub>C</sub> , Q <sub>D</sub>			14	22	ns
t <sub>PHL</sub>					35	50	
t <sub>PLH</sub>	Clock	Ripple Clock			13	20	ns
t <sub>PHL</sub>					16	24	
t <sub>PLH</sub>	Clock	Q <sub>A</sub> , Q <sub>B</sub> , Q <sub>C</sub> , Q <sub>D</sub>			16	24	ns
t <sub>PHL</sub>					24	36	
t <sub>PLH</sub>	Clock	Max/Min			28	42	ns
t <sub>PHL</sub>					37	52	
t <sub>PLH</sub>	Down/Up	Ripple Clock			30	45	ns
t <sub>PHL</sub>					30	45	
t <sub>PLH</sub>	Down/Up	Max/Min			21	33	ns
t <sub>PHL</sub>					22	33	

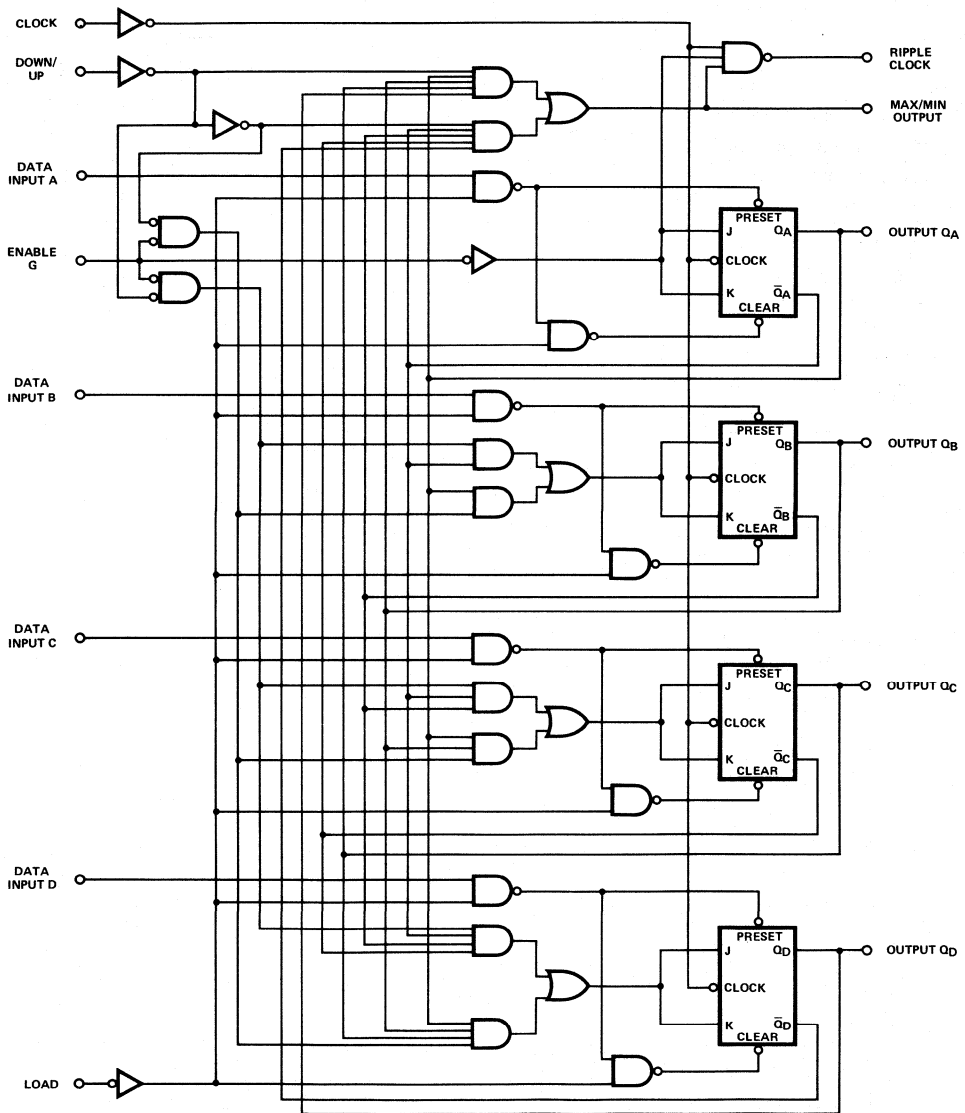
<sup>1</sup>f<sub>max</sub> = maximum clock frequency

t<sub>PLH</sub> = propagation delay time, low-to-high-level output

t<sub>PHL</sub> = propagation delay time, high-to-low-level output

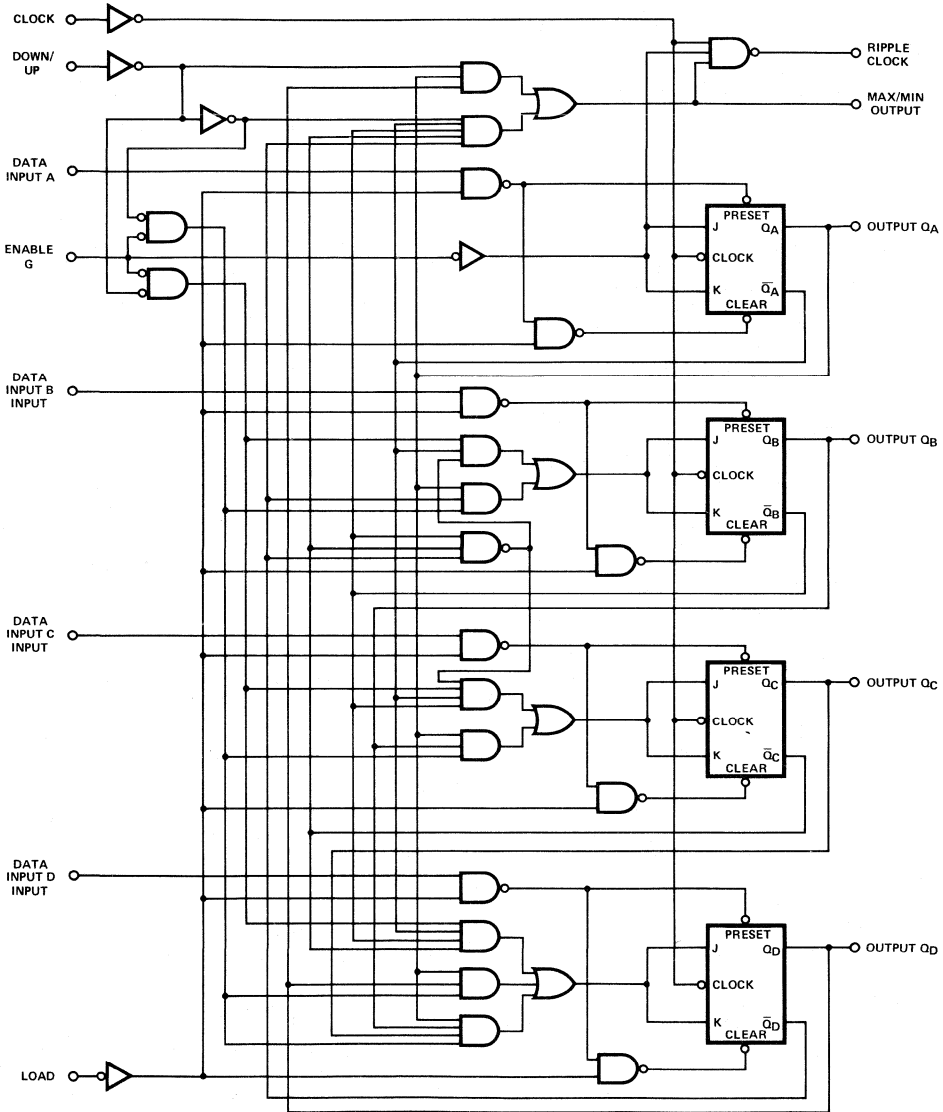
BLOCK DIAGRAM

DECADE COUNTERS, 54190, 74190



BLOCK DIAGRAM

BINARY COUNTERS, 54191, 74191



### DESCRIPTION

This is a synchronous reversible (up/down) counter having a complexity of 55 equivalent gates. The S54192 and N74192 are BCD counters. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincidentally with each other when so instructed by the steering logic. This mode of operation eliminates the output counting spikes which are normally associated with asynchronous (ripple-clock) counters.

The outputs of the master-slave flip-flops are triggered by a low-to-high-level transition of either count (clock) input. The direction of counting is determined by which count input is pulsed while the other count input is high.

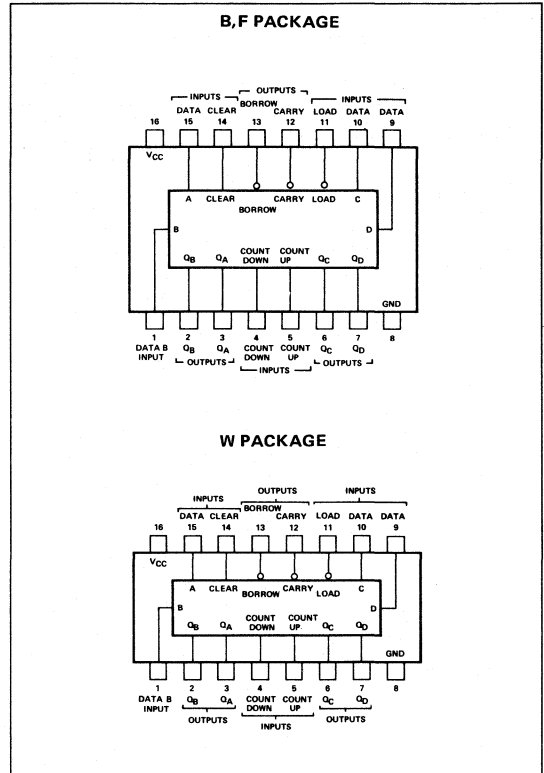
These counters are fully programmable; that is, the outputs may be present to any state by entering the desired data at the data inputs while the load input is low. The output will change to agree with the data inputs independently of the count pulses. This feature allows the counters to be used as modulo-N dividers by simply modifying the count length with the preset inputs.

A clear input has been provided which forces all outputs to the low level when a high level is applied. The clear function is independent of the count and load inputs. An input buffer has been placed on the clear, count, and load inputs to lower the drive requirements to one normalized Series 54/74 load. This is important when the output of the driving circuitry is somewhat limited.

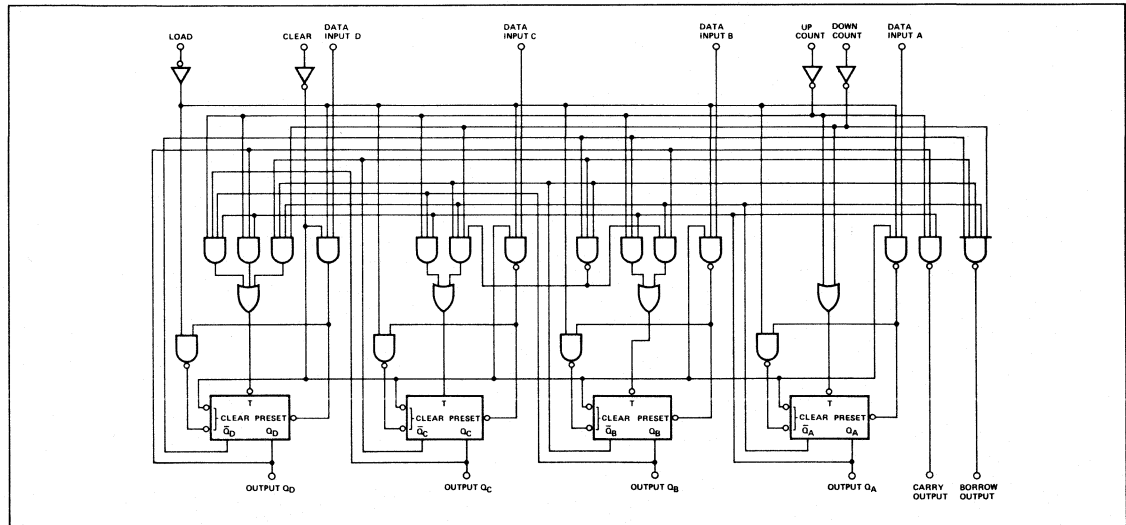
These counters were designed to be cascaded without the need for external circuitry. Both borrow and carry outputs are available to cascade both the up-and down-counting functions. The borrow output produces a pulse equal in width to the count-down input when the counter underflows. Similarly, the carry output produces a pulse equal in width to the count-up input when an overflow condition exists. The counters can then be easily cascaded by feeding the borrow and carry outputs to the count-down and count-up inputs respectively of the succeeding counter.

Power dissipation is typically 325 milliwatts for either the decade or binary version. Maximum input count frequency is typically 32 megahertz and is guaranteed to be 25MHz minimum.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM

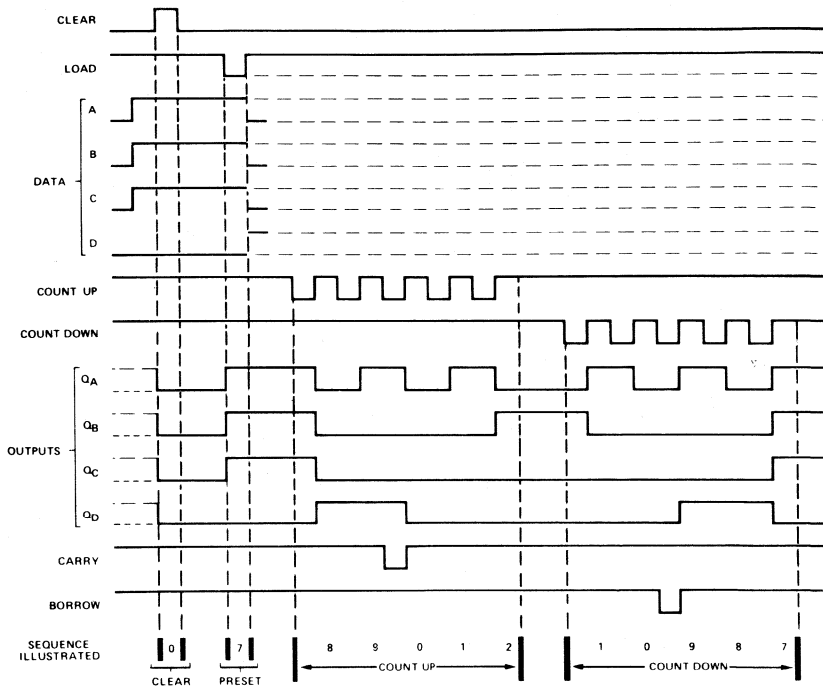


# SIGNETICS SYNCHRONOUS DECADE UP/DOWN COUNTER WITH PRESET INPUTS ■ S54/N74192

## DECADE COUNTER (typical clear, load, and count sequences)

Illustrated below is the following sequence:

1. Clear outputs to zero.
2. Load (preset) to BCD seven.
3. Count up to eight, nine, carry, zero, one, and two.
4. Count down to one, zero, borrow, nine, eight, and seven.

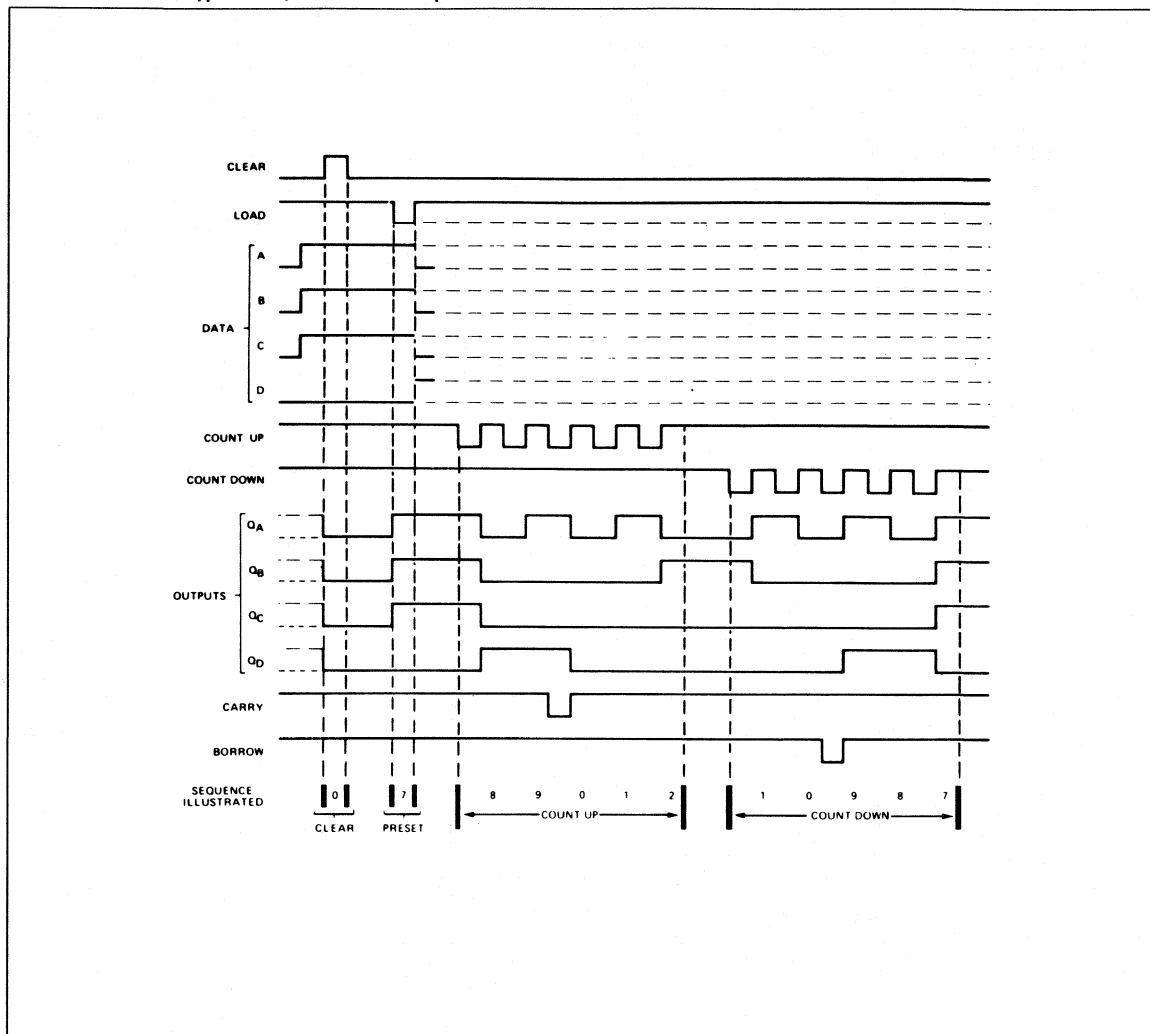


### NOTES:

A. Clear overrides load, data, and count inputs.

B. When counting up, count-down input must be high; when counting down, count-up input must be high.

DECADE COUNTER typical clear, load and count sequences



NOTES:

- A. Clear overrides load, data, and count inputs.
- B. When counting up, count-down input must be high; when counting down, count-up input must be high.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SN54192			SN74192			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
High-level output current, $I_{OH}$			-400			-400	$\mu A$
Low-level output current, $I_{OL}$			16			16	mA
Count frequency, $f_{count}$	0		25	0		25	MHz
Width of any input pulse, $t_{wq}$	20			20			ns
Data setup time, $t_{setup}$	20			20			ns
Data hold time, $t_{hold}$	0			0			ns
Operating free-air temperature, $T_A$	-55		125	0		70	$^{\circ}C$

# SIGNETICS SYNCHRONOUS DECADE UP/DOWN COUNTER WITH PRESET INPUTS ■ S54/N74192

SWITCHING CHARACTERISTICS.  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER *	FROM INPUT	TO OUTPUT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$				25	32		MHz
$t_{PLH}$	Count-up	Carry	CL = 15pF, R <sub>L</sub> = 400Ω, See Figures 1 and 2	17	17	26	ns
$t_{PHL}$				16	24		
$t_{PLH}$				16	24		
$t_{PHL}$	Count-down	Borrow		16	16	24	ns
$t_{PLH}$				25	38		
$t_{PHL}$				31	47		
$t_{PLH}$	Either Count	Q		27	40	ns	
$t_{PHL}$				29	40		
$t_{PLH}$	Load	Q		22	35	ns	
$t_{PHL}$			22	35			

\* $f_{max}$  = maximum clock frequency  
 $t_{PLH}$  = propagation delay time, low-to-high-level output  
 $t_{PHL}$  = propagation delay time, high-to-low-level output

### ELECTRICAL CHARACTERISTICS OVER RECOMMENDED OPERATING FREE AIR TEMPERATURE RANGE (unless otherwise noted)

PARAMETER	TEST CONDITIONS*	SN54192			SN74192			UNIT	
		MIN	TYP**	MAX	MIN	TYP**	MAX		
$V_{IH}$	High-level input voltage	2			2			V	
$V_{IL}$	Low-level input voltage			0.8			0.8	V	
$V_I$	Input clamp voltage			-1.5			-1.5	V	
$V_{OH}$	High-level output voltage	$V_{CC} = MIN, I_I = -12mA$						V	
$V_{OL}$	Low-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OH} = -400\mu A$	2.4	3.4		2.4	3.4	V	
$I_I$	Input current at maximum input voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OL} = 16mA$		0.2	0.4		0.2	0.4	V
$I_{IH}$	High-level input current	$V_{CC} = MAX, V_I = 5.5V$					1	1	mA
$I_{IL}$	Low-level input current	$V_{CC} = MAX, V_I = 2.4V$					40	40	$\mu A$
$I_{OS}$	Short-circuit output current†	$V_{CC} = MAX, V_I = 0.4V$					-1.6	-1.6	mA
$I_{CC}$	Supply current	$V_{CC} = MAX$ , See Note 2	-20		-65	-18		-65	mA
				65	89		65	102	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

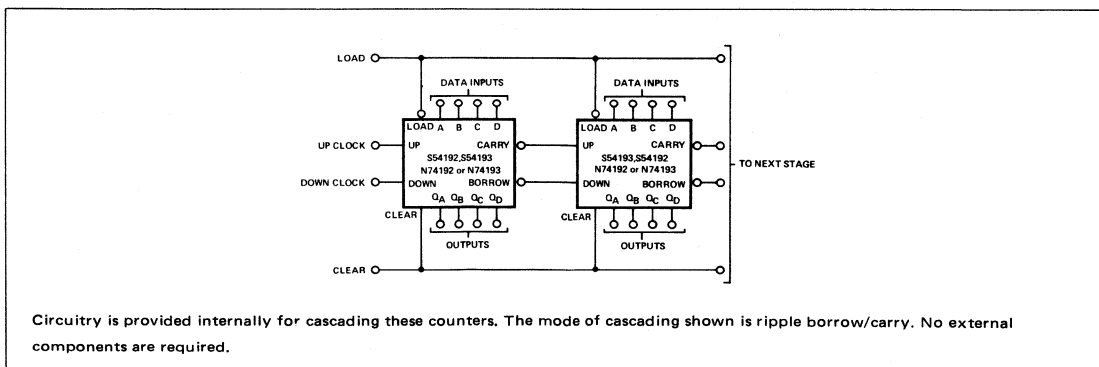
\*\*All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

†Not more than one output should be shorted at a time.

NOTE 2:

$I_{CC}$  is measured with all outputs open, clear and load inputs grounded, and all other inputs at 4.5V.

### CASCADING



### DESCRIPTION

The S54193 and N74193 are 4-bit binary counters. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincidentally with each other when so instructed by the steering logic. This mode of operation eliminates the output counting spikes which are normally associated with asynchronous (ripple-clock) counters.

The outputs of the four master-slave flip-flops are triggered by a low-to-high-level transition of either count (clock) input. The direction of counting is determined by which count input is pulsed while the other count input is high.

All four counters are fully programmable; that is, the outputs may be preset to any state by entering the desired data at the data inputs while the load input is low. The output will change to agree with the data inputs independently of the count pulses. This feature allows the counters to be used as modulo-N dividers by simply modifying the count length with the preset inputs.

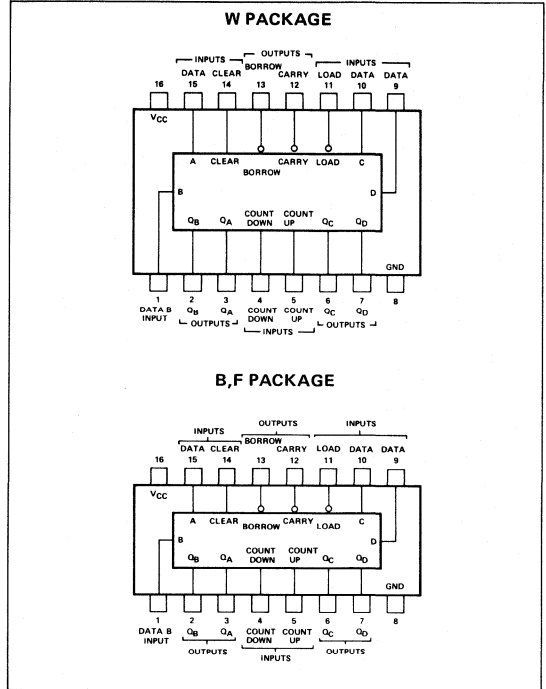
A clear input has been provided which forces all outputs to the low level when a high level is applied. The clear function is independent of the count and load inputs. An input buffer has been placed on the clear, count, and load inputs to lower the drive requirements to one normalized Series 54/74 load. This is important when the output of the driving circuitry is somewhat limited.

These counters were designed to be cascaded without the need for external circuitry. Both borrow and carry outputs are available to cascade both the up- and down-counting functions. The borrow output produces a pulse equal in width to the count-down input when the counter underflows. Similarly, the carry output produces a pulse equal in width to the count-up input when an overflow condition exists. The counters can then be easily cascaded by feeding the borrow and carry outputs to the count-down and count-up inputs respectively of the succeeding counter.

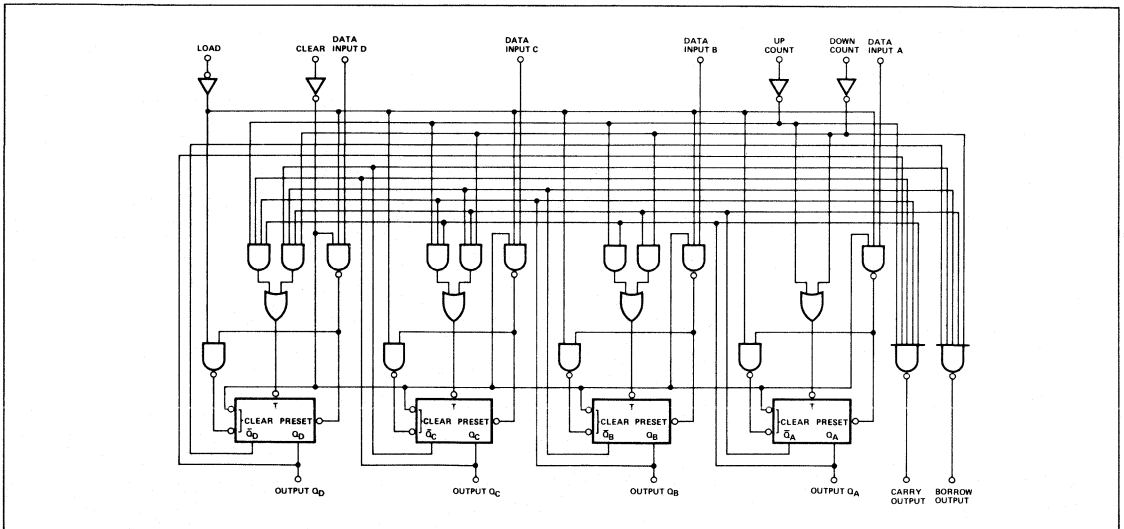
Power dissipation is typically 325 milliwatts for either the decade or binary version. Maximum input count frequency is typically 32 megahertz and is guaranteed to be 25MHz minimum. All inputs are

buffered and represent only one normalized Series 54/74 load. Input clamping diodes are provided to minimize transmission-line effects and thereby simplify system design.

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



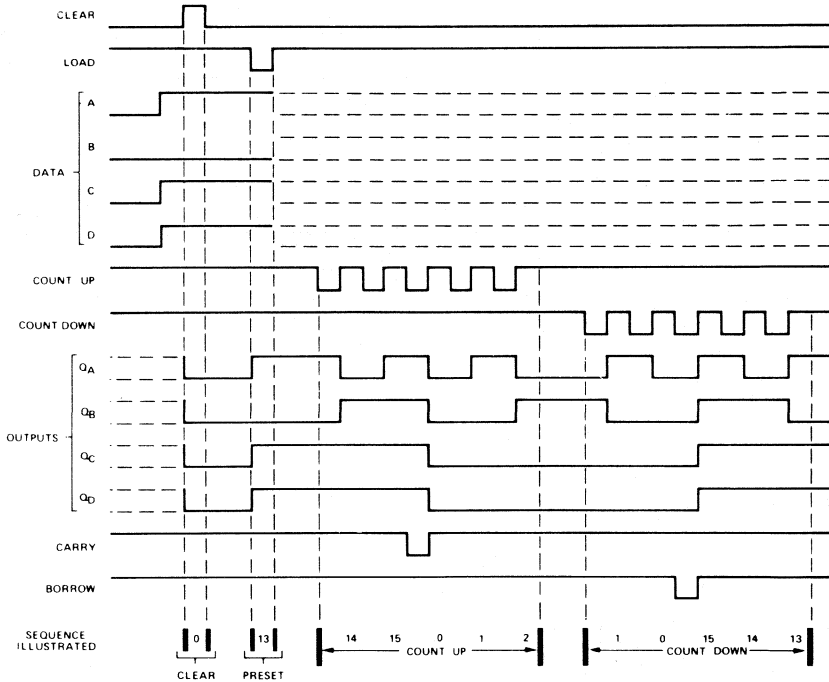


# SIGNETICS SYNCHRONOUS 4-BIT BINARY UP/DOWN COUNTER ■ S54/N74193

## BINARY COUNTER (typical clear, load, and count sequences)

Illustrated below is the following sequence:

1. Clear outputs to zero.
2. Load (preset) to BCD seven.
3. Count up to eight, nine, carry, zero, one, and two.
4. Count down to one, zero, borrow, nine, eight, and seven.



### NOTES:

- A. Clear overrides load, data, and count inputs.
- B. When counting up, count-down input must be high; when counting down, count-up input must be high.

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	SN54193			SN74193			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
High-level output current, $I_{OH}$			-400			-400	$\mu A$
Low-level output current, $I_{OL}$			16			16	mA
Count frequency, $f_{count}$	0		25	0		25	MHz
Width of any input pulse, $t_{Wq}$	20			20			ns
Data setup time, $t_{setup}$	20			20			ns
Data hold time, $t_{hold}$	0			0			ns
Operating free-air temperature, $T_A$	-55		125	0		70	$^{\circ}C$

# SIGNETICS SYNCHRONOUS DECADE UP/DOWN COUNTER WITH PRESET INPUTS ■ S54/N74193

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER *	FROM INPUT	TO OUTPUT	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$				25	32		MHz
$t_{PLH}$	Count-up	Carry	CL = 15pF, R <sub>L</sub> = 400Ω, See Figures 1 and 2	17	17	26	ns
$t_{PHL}$				16	24		
$t_{PLH}$				16	24		
$t_{PHL}$	Count-down	Borrow		16	24	ns	
$t_{PLH}$				25	38		
$t_{PHL}$				31	47		
$t_{PLH}$	Either Count	Q		27	40	ns	
$t_{PHL}$				29	40		
$t_{PLH}$	Load	Q		22	35	ns	
$t_{PHL}$	Clear	Q					

\* $f_{max}$  = maximum clock frequency  
 $t_{PLH}$  = propagation delay time, low-to-high-level output  
 $t_{PHL}$  = propagation delay time, high-to-low-level output

## ELECTRICAL CHARACTERISTICS OVER RECOMMENDED OPERATING FREE AIR TEMPERATURE RANGE (unless otherwise noted)

PARAMETER	TEST CONDITIONS*	SN54193			SN74193			UNIT	
		MIN	TYP**	MAX	MIN	TYP**	MAX		
$V_{IH}$	High-level input voltage	2			2			V	
$V_{IL}$	Low-level input voltage			0.8			0.8	V	
$V_I$	Input clamp voltage			-1.5			-1.5	V	
$V_{OH}$	High-level output voltage	$V_{CC} = MIN,$ $V_{IH} = 2V,$ $V_{IL} = 0.8V,$ $I_{OH} = -400\mu A$	2.4	3.4		2.4	3.4	V	
$V_{OL}$	Low-level output voltage	$V_{CC} = MIN,$ $V_{IH} = 2V,$ $V_{IL} = 0.8V,$ $I_{OL} = 16mA$		0.2	0.4		0.2	0.4	V
$I_I$	Input current at maximum input voltage	$V_{CC} = MAX,$ $V_I = 5.5V$		1			1	mA	
$I_{IH}$	High-level input current	$V_{CC} = MAX,$ $V_I = 2.4V$		40			40	$\mu A$	
$I_{IL}$	Low-level input current	$V_{CC} = MAX,$ $V_I = 0.4V$		-1.6			-1.6	mA	
$I_{OS}$	Short-circuit output current†	$V_{CC} = MAX$	-20	-65		-18	-65	mA	
$I_{CC}$	Supply current	$V_{CC} = MAX,$ See Note 2		65	89		65	102	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

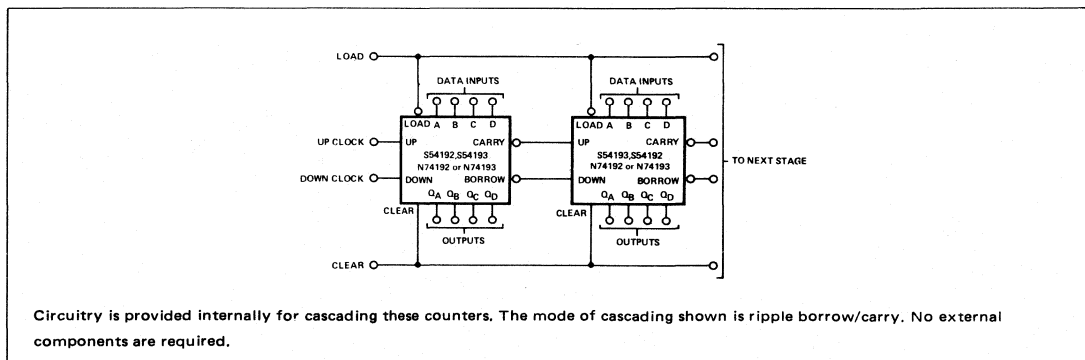
\*\*All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

†Not more than one output should be shorted at a time.

NOTE 2:

$I_{CC}$  is measured with all outputs open, clear and load inputs grounded, and all other inputs at 4.5V.

## CASCADING



### DESCRIPTION

These bidirectional shift registers are designed to incorporate virtually all of the features a system designer may want in a shift register. The circuit contains 46 equivalent gates and features parallel inputs, parallel outputs, right-shift and left-shift serial inputs, operating-mode-control inputs, and a direct overriding clear line. The register has four distinct modes of operation, namely:

	MODE CONTROL	
	S1	S0
Parallel (Broadside) Load	H	H
Shift Right (In the direction $Q_A$ toward $Q_D$ )	L	H
Shift Left (In the direction $Q_D$ toward $Q_A$ )	H	L
Inhibit Clock (Hold)	L	L

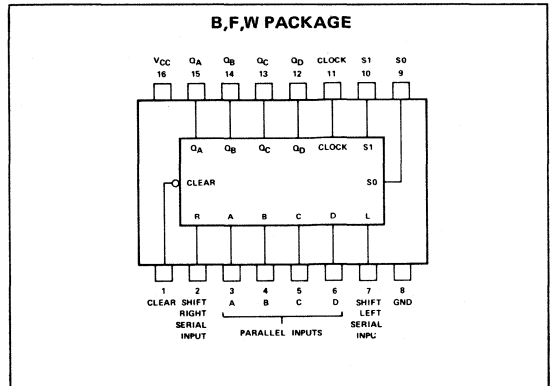
In the parallel-load mode, data is loaded into the associated flip-flop and appears at the outputs after the positive transition of the clock input. During loading, serial data flow is inhibited. Shift right is accomplished synchronously with the rising edge of the clock pulse when S0 is high and S1 is low. Serial data for this mode is entered at the shift-right data input. When S0 is low and S1 is high, data shifts left synchronously and new data is entered at the shift-left serial input. Clocking of the flip-flops is inhibited when both mode-control inputs are low. The mode controls should be changed only while the clock input is high.

These 4-bit shift registers are compatible with most other TTL and DTL logic families. All inputs are buffered to lower the drive requirements to one normalized Series 54/74 load, and input clamp-

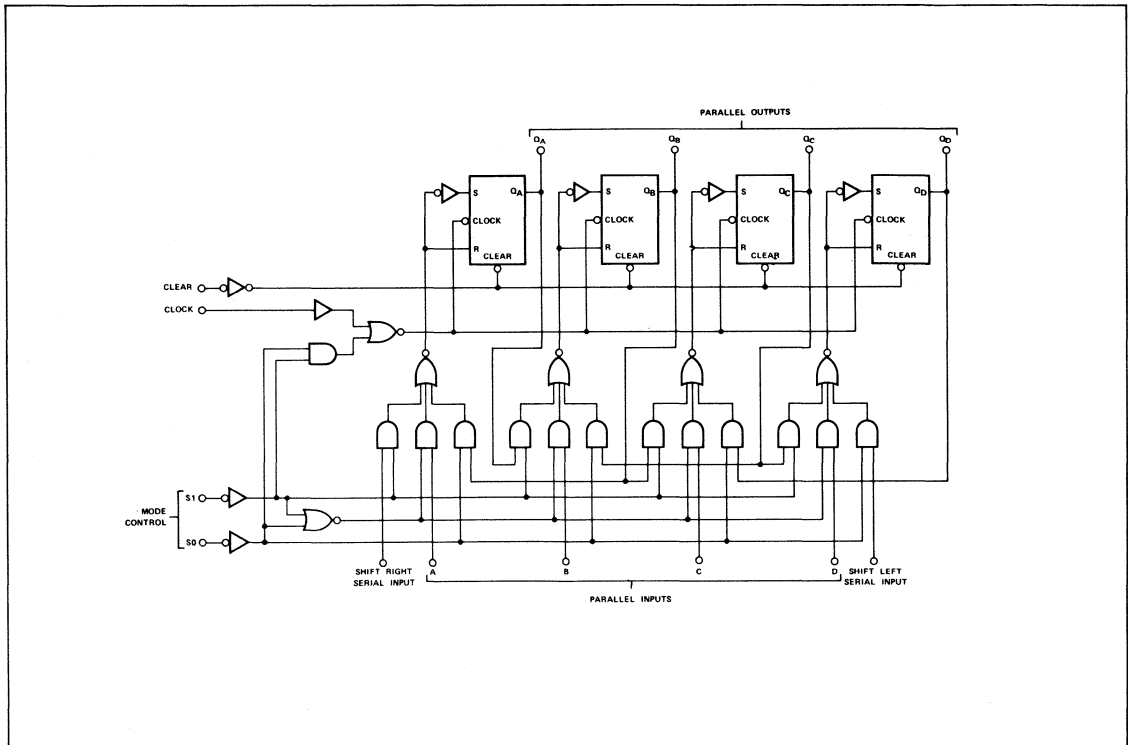
ing diodes minimize switching transients to simplify system design. Maximum input clock frequency is typically 36 megahertz and power dissipation is typically 195mW.

The S54194 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74194 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### PIN CONFIGURATIONS



### LOGIC DIAGRAM



# SIGNETICS 4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTERS ■ S54194, N74194

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54194			N74194			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level		20	High logic level		20	
	Low logic level		10	Low logic level		10	
Input Clock Frequency, $f_{clock}$	0		25	0		25	MHz
Width of Clock or Clear Pulse, $t_w$	20			20			ns
Setup Time, $t_{setup}$ :	Mode control		30	Mode control		30	ns
	Serial and parallel data		20	Serial and parallel data		20	ns
	Clear inactive-state		25	Clear inactive-state		25	ns
Hold Time at any Input, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{IH}$	High-level input voltage	2			V	
$V_{IL}$	Low-level input voltage			0.8	V	
$I_I$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$		-1.5	V	
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -800\mu\text{A}$	2.4		V	
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 16\text{mA}$		0.4	V	
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$		1	mA	
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$		40	$\mu\text{A}$	
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$		-1.6	mA	
$I_{OS}$	Short-circuit output current †	$V_{CC} = \text{MAX}$		-20	-57	mA
			S54194 N74194	-18	-57	
$I_{CC}$	Supply current	$V_{CC} = \text{MAX},$ See Note 2		39	63	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$f_{max}$	Maximum input clock frequency	25	36		MHz	
$t_{PHL}$	Propagation delay time, high-to-	$C_L = 15\text{pF}, R_L = 400\Omega$		19	30	ns
	low-level output from clear					
$t_{PLH}$	Propagation delay time, low-to-		7	14	22	ns
	high-level output from clock					
$t_{PHL}$	Propagation delay time, high-to-		7	17	26	ns
	low-level output from clock					

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .  
Not more than one output should be shorted at a time.

### DESCRIPTION

These 4-bit registers feature parallel inputs, parallel outputs, J-K serial inputs, shift/load control input, and a direct overriding clear.

The registers have two modes of operation:

Parallel (Broadside) Load

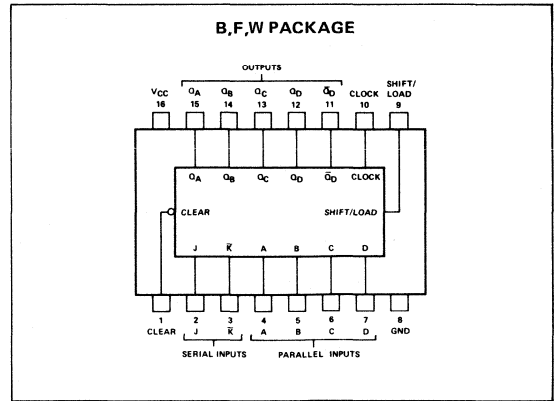
Shift (In direction  $Q_A$  toward  $Q_D$ )

Parallel loading is accomplished by applying the 4 bits of data and taking the shift/load control input low. The data are loaded into the associated flip-flop and appears at the outputs after the positive transition of the clock input. During loading, serial data flow is inhibited.

Shifting is accomplished synchronously when the shift/load control input is high. Serial data for this mode are entered at the J-K inputs. These inputs permit the first stage to perform as a J-K, D-, or T-type flip-flop as shown in the truth table.

These shift registers are fully compatible with most other TTL and DTL families. All inputs are buffered to lower the drive requirements to one normalized Series 54/74 load, including the clock input. Maximum input clock frequency is typically 39 megahertz and power dissipation is typically 195 milliwatts. The S54195 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74195 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

### PIN CONFIGURATIONS



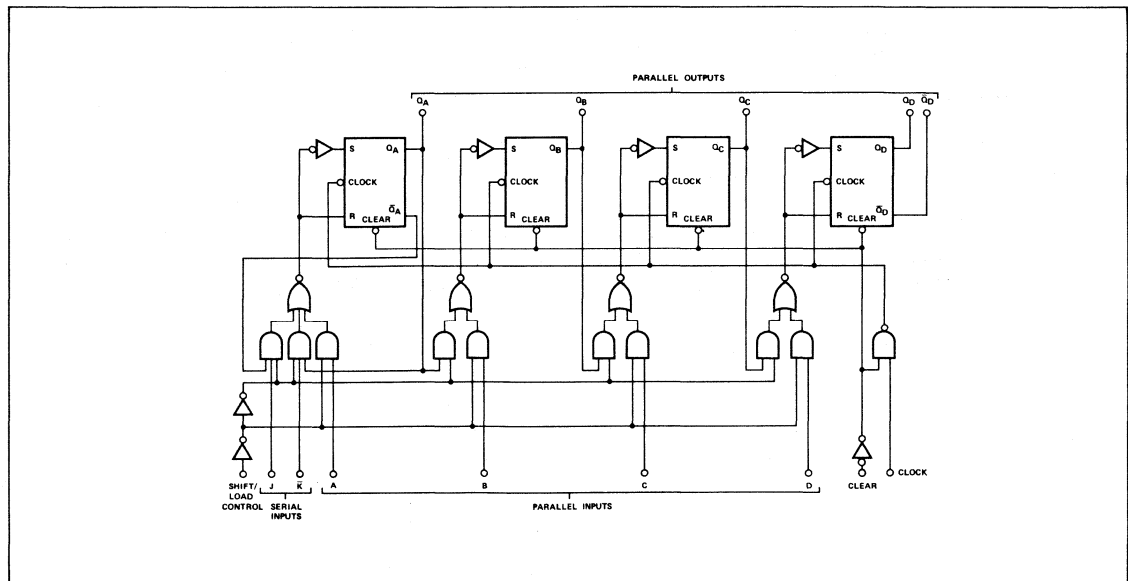
### TRUTH TABLE

Inputs at $t_n$		Outputs at $t_{n+1}$				
J	K	$Q_A$	$Q_B$	$Q_C$	$Q_D$	$\bar{Q}_D$
L	H	$Q_{An}$	$Q_{An}$	$Q_{Bn}$	$Q_{Cn}$	$\bar{Q}_{Cn}$
L	L	L	$Q_{An}$	$Q_{Bn}$	$Q_{Cn}$	$\bar{Q}_{Cn}$
H	H	$\bar{Q}_{An}$	$Q_{An}$	$Q_{Bn}$	$Q_{Cn}$	$\bar{Q}_{Cn}$
H	L	$\bar{Q}_{An}$	$Q_{An}$	$Q_{Bn}$	$Q_{Cn}$	$\bar{Q}_{Cn}$

H = High Level, L = Low Level

- NOTES
- $t_n$  = bit time before clock pulse
  - $t_{n+1}$  = bit time after clock pulse
  - $Q_{An}$  = state of  $Q_A$  at  $t_n$

### LOGIC DIAGRAM



# SIGNETICS 4-BIT PARALLEL-ACCESS SHIFT REGISTER ■ S54195, N74195

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54195			N74195			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level		20	High logic level		20	
	Low logic level		10	Low logic level		10	
Input Clock Frequency, $f_{clock}$	0		30	0		30	MHz
Width of Clock Input Pulse, $t_w(\text{clock})$	16			16			ns
Width of Clear Input Pulse, $t_w(\text{clear})$	12			12			ns
Setup Time, $t_{setup}$ :	Shift/load		25	Shift/load		25	
	Serial and parallel data		15	Serial and parallel data		15	ns
	Clear inactive-state		25	Clear inactive-state		25	
Shift/Load Release Time, $t_{release}$			10			10	ns
Serial and Parallel Data Hold Time, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP**	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$I_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -800\mu\text{A}$	2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 16\text{mA}$			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			40	$\mu\text{A}$
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$			-1.6	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = \text{MAX}$	S54195 -20		-57	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ See Note	N74195 -18	39	-57 63	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum input clock frequency		30	39		MHz
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear			19	30	ns
$t_{PLH}$ Propagation delay time, low-to-high-level output from clock	$C_L = 15\text{pF}, R_L = 400\Omega$	6	14	22	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clock		7	17	26	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time.

NOTE With all outputs open, shift/load grounded, and 4.5V applied to the J, R, and data inputs,  $I_{CC}$  is measured by applying a momentary ground, followed by 4.5V, to clear, and then applying a momentary ground, followed by 4.5V, to clock.

### DESCRIPTION

These 8-bit shift registers are compatible with most other TTL, DTL, and MSI logic families. All inputs are buffered to lower the drive requirements to one normalized Series 54/74 load, and input clamping diodes minimize switching transients to simplify system design. Maximum input clock frequency is typically 35 megahertz and power dissipation is typically 360 mW.

All Series 54 devices are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . Series 74 devices are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

The bidirectional registers are designed to incorporate virtually all of the features a system designer may want in a shift register. These circuits contain 87 equivalent gates and feature parallel inputs, parallel outputs, right-shift and left-shift serial inputs, operating-mode-control inputs, and a direct overriding clear line. The register has four distinct modes of operation, namely:

- Parallel (Broadside) Load
- Shift Right (In the direction  $Q_A$  toward  $Q_H$ )
- Shift Left (In the direction  $Q_H$  toward  $Q_A$ )
- Inhibit Clock (Do nothing)

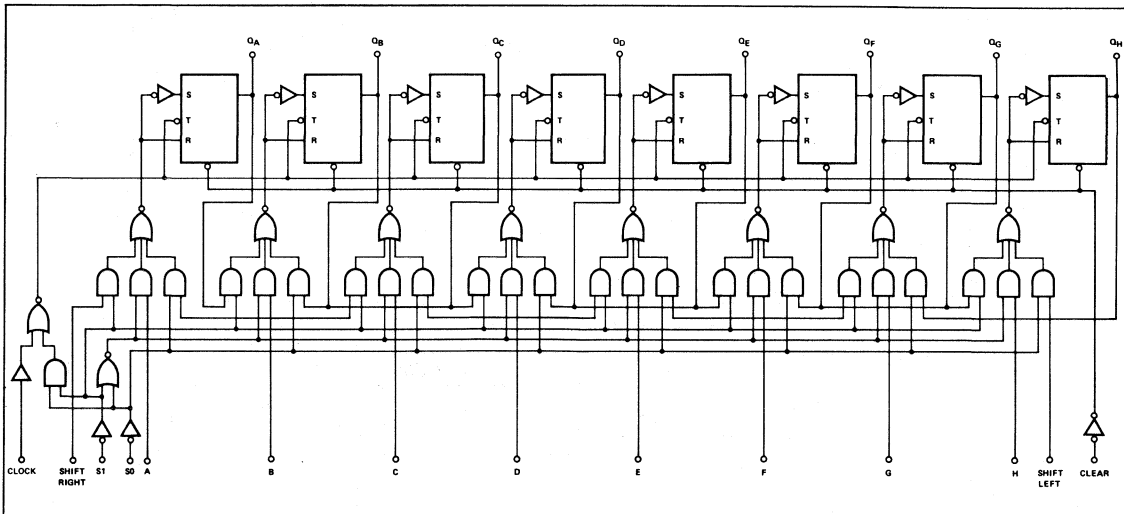
Synchronous parallel loading is accomplished by applying the 8 bits of data and taking both mode control inputs,  $S_0$  and  $S_1$ , high. The data is loaded into the associated flip-flop and appears at the outputs after the positive transition of the clock input. During loading, serial data flow is inhibited.

Shift right is accomplished synchronously with the rising edge of the clock pulse when  $S_0$  is high and  $S_1$  is low. Serial data for this mode is entered at the shift-right data input. When  $S_0$  is low and  $S_1$  is high, data shifts left synchronously and new data is entered at the shift-left serial input.

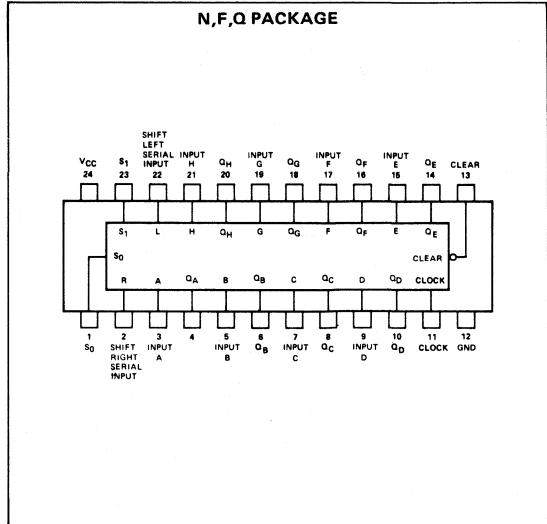
Clocking of the flip-flop is inhibited when both mode control inputs are low. The mode controls should be changed only while the clock input is high.

Average power dissipation per gate is typically 4.15 mW.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS



### TRUTH TABLE

OPERATION OF MODE CONTROL		
INPUTS		MODE
$S_1$	$S_0$	
L	L	INHIBIT CLOCK
H	L	SHIFT LEFT
L	H	SHIFT RIGHT
H	H	PARALLEL LOAD

# SIGNETICS 8-BIT SHIFT REGISTERS ■ S54198, N74198

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54198			N74198			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:			20			20	
High logic level			10			10	
Low logic level			25			25	
Input Count Frequency, $f_{count}$	0		25	0		25	MHz
Width of Clock or Clear Pulse, $t_w$	20			20			ns
Mode-Control Setup Time, $t_{setup}$	30			30			ns
Data Setup Time, $t_{setup}$	20			20			ns
Hold Time at any Input, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54198			N74198			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage	$V_{CC} = MAX, I_I = -12mA$			-1.5			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OH} = -800\mu A$	2.4			2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OL} = 16mA$			0.4			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = MAX, V_I = 5.5V$			1			1	mA
$I_{IH}$ High-level input current	$V_{CC} = MAX, V_I = 2.4V$			40			40	$\mu A$
$I_{IL}$ Low-level input current	$V_{CC} = MAX, V_I = 0.4V$			-1.6			-1.6	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = MAX$	-20		-57	-18		-57	mA
$I_{CC}$ Supply current	$V_{CC} = MAX, Table Below$		72	104		72	116	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum input count frequency		25	35		MHz
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear	$C_L = 15pF, R_L = 400\Omega$		23	35	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clock		8	20	30	ns
$t_{PLH}$ Propagation delay time, low-to-high-level output from clock		8	17	26	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

## TEST CONDITIONS FOR $I_{CC}$ (all outputs are open)

TYPE	APPLY 4.5V	FIRST GROUND, THEN APPLY 4.5V	GROUND
S54198, N74198	Serial input, $S_0, S_1$	Clock	Clear, Inputs A thru H



#### DESCRIPTION

These 8-bit shift registers are compatible with most other TTL, DTL, and MSI logic families. All inputs are buffered to lower the drive requirements to one normalized Series 54/74 load, and input clamping diodes minimize switching transients to simplify system design. Maximum input clock frequency is typically 35 megahertz and power dissipation is typically 360 mW.

These synchronous 8-bit registers feature parallel inputs, parallel outputs, J-K serial inputs, shift/load control input, a direct overriding clear line, and gated clock inputs. The register has three modes of operation:

- Parallel (Broadside) Load
- Shift (In the direction  $Q_A$  toward  $Q_H$ )
- Inhibit Clock (Do nothing)

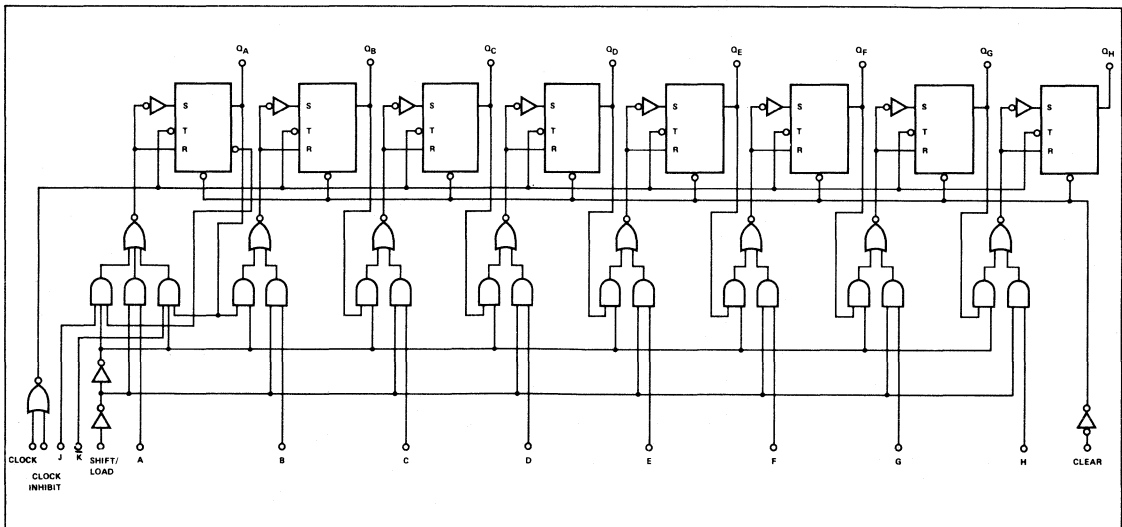
Parallel loading is accomplished by applying the 8 bits of data and taking the shift/load control input low when the clock input is not inhibited. The data is loaded into the associated flip-flop and appears at the outputs after the positive transition of the clock input. During loading, serial data flow is inhibited.

Shifting is accomplished synchronously when shift/load is high and the clock input is not inhibited. Serial data for this mode is entered at the J-K inputs. See the J-K inputs truth table for states required to enter serial data into the first flip-flop.

Both of the clock inputs are identical in function and may be used interchangeably to serve as clock or clock-inhibit inputs. Holding either high inhibits clocking, but when one is held low, a clock input applied to the other input is passed to the eight flip-flops of the register. The clock-inhibit input should be changed to the high level only while the clock input is high.

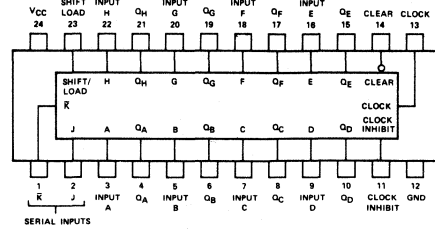
These shift registers contain the equivalent of 79 TTL gates. Average power dissipation per gate is typically 4.55 mW.

#### LOGIC DIAGRAM



#### PIN CONFIGURATIONS

##### N,F,Q PACKAGES



†Pin assignments for these circuits are the same for packages.

#### TRUTH TABLE

INPUTS at $t_n$		OUTPUT $t_{n+1}$
J	$\bar{K}$	$Q_A$
L	H	$Q_{An}$
L	L	L
H	H	H
H	L	$\bar{Q}_{An}$

#### NOTES:

- A.  $t_n$  = bit time before clock pulse
- B.  $t_{n+1}$  = bit time after clock pulse

H - high level, L = low level

# SIGNETICS 8-BIT SHIFT REGISTERS ■ S54199, N74199

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54199			N74199			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out From each output, N: High logic level			20			20	
Low logic level			10			10	
Input Count Frequency, $f_{count}$	0		25	0		25	MHz
Width of Clock or Clear Pulse, $t_w$	20			20			ns
Mode-Control Setup Time, $t_{setup}$	30			30			ns
Data Setup Time, $t_{setup}$	20			20			ns
Hold Time at any Input, $t_{hold}$	0			0			ns
Operating Free-Air Temperature, $T_A$	-55	25	125	0	25	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	S54199			N74199			UNIT
		MIN	TYP*	MAX	MIN	TYP*	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage	$V_{CC} = MAX, I_I = -12mA$			-1.5			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OH} = -800\mu A$	2.4			2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = MIN, V_{IH} = 2V, V_{IL} = 0.8V, I_{OL} = 16mA$			0.4			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = MAX, V_I = 5.5V$			1			1	mA
$I_{IH}$ High-level input current	$V_{CC} = MAX, V_I = 2.4V$			40			40	$\mu A$
$I_{IL}$ Low-level input current	$V_{CC} = MAX, V_I = 0.4V$			-1.6			-1.6	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = MAX$	-20		-57	-18		-57	mA
$I_{CC}$ Supply current	$V_{CC} = MAX, Table Below$		72	104		72	116	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum input count frequency		25	35		MHz
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear			23	35	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clock	$C_L = 15pF, R_L = 400\Omega$	8	20	30	ns
$t_{PLH}$ Propagation delay time, low-to-high-level output from clock		8	17	26	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time.

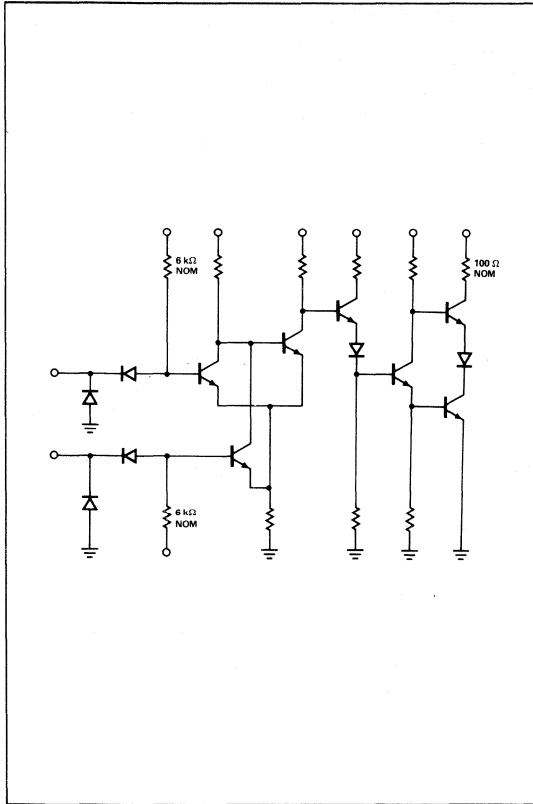
## TEST CONDITIONS FOR $I_{CC}$ (all outputs are open)

TYPE	APPLY 4.5V	FIRST GROUND, THEN APPLY 4.5V	GROUND
S54199, N74199	J, $\bar{K}$ , Inputs A thru H	Clock	Clock Inhibit, Clear, Shift/Load

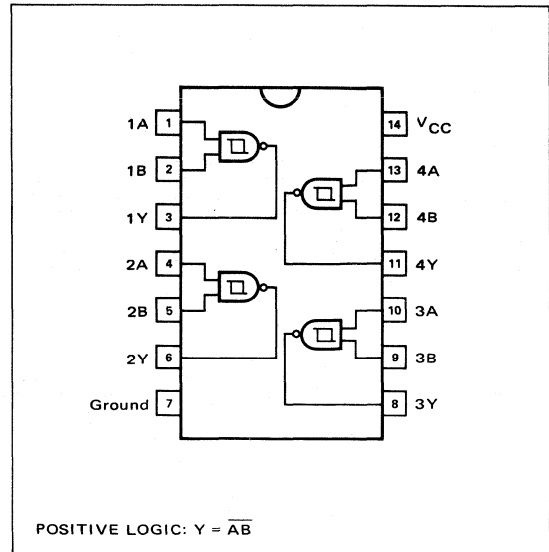
### DESCRIPTION

The 54/74232 is the NOR version of the 54/74132. The specifications for the 54/74232 are similar to the 54/74132. The only exception being 4mA's added to the typical of maximum I<sub>CC</sub> parameters.

### SCHEMATIC



### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS (over operating free-air temperature range. (Unless otherwise noted)

Supply voltage, V <sub>CC</sub> (see Note 1)	7V
Input voltage	5.5V
Interemitter voltage: S54232, N74232 Circuits only (see Note 2)	5.5V
Operating free-air temperature range:	
S54232 Circuits	-55°C to 125°C
N74232 Circuits	0°C to 70°C
Storage temperature range	-65°C to 150°C

### NOTES:

1. Voltage values, except interemitter voltage, are with respect to the network ground terminal.
2. This is the voltage between two emitters of a multiple-emitter transistor. For S54232/N74232 circuits, this rating applies between the two inputs of any gate.

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54232			N74232			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20	20			
	Low logic level		10	10			
Operating free-air temperature, T <sub>A</sub>	-55		125	0		70	°C
Maximum input rise and fall times	No restriction			No restriction			

**ELECTRICAL CHARACTERISTICS** (Over recommended operating free-air temperature range. Unless otherwise noted.)

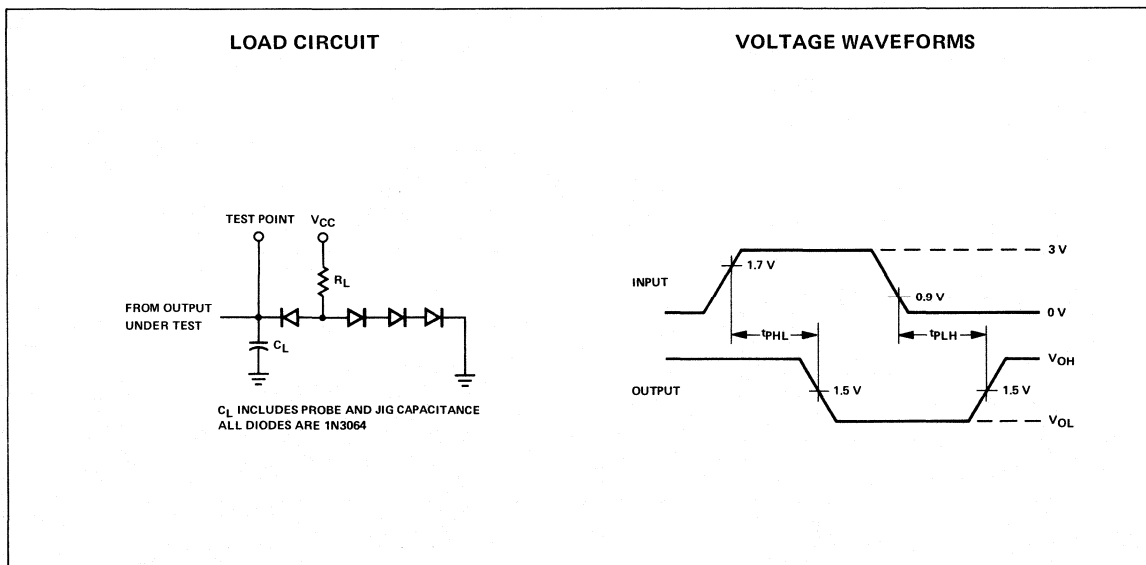
SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	MIN	TYP <sup>2</sup>	MAX	UNIT
V <sub>T+</sub>	Positive-going threshold voltage	V <sub>CC</sub> = 5V	1.5	1.7	2	V
V <sub>T-</sub>	Negative-going threshold voltage	V <sub>CC</sub> = 5V	0.6	0.9	1.1	V
V <sub>T+</sub> - V <sub>T-</sub>	Hysteresis	V <sub>CC</sub> = 5V	0.4	0.8		V
V <sub>I</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -12mA			-1.5	V
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>I</sub> = 0.6V I <sub>OH</sub> = -800μA	2.4	3.3		V
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>I</sub> = 2V, I <sub>OL</sub> = 16mA		0.22	0.4	V
I <sub>T+</sub>	Input current at positive-going threshold	V <sub>CC</sub> = 5V, V <sub>I</sub> = V <sub>T+</sub>	-0.43			mA
I <sub>T-</sub>	Input current at negative-going threshold	V <sub>CC</sub> = 5V, V <sub>I</sub> = V <sub>T-</sub>	-0.56			mA
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1	mA
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.4V			40	μA
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4V		-0.8	-1.2	mA
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX	-18		-55	mA
I <sub>CCH</sub>	Supply current, high-level outputs	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0		19	28	mA
I <sub>CCL</sub>	Supply current, low-level outputs	V <sub>CC</sub> = MAX, V <sub>I</sub> = 4.5V		30	44	mA

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.
2. All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.
3. Not more than one output should be shorted at a time.

**SWITCHING CHARACTERISTICS** (V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C, N = 10)

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 400Ω		15	22	ns
t <sub>PHL</sub>	Propagation delay time, high-to low-level output	See Figure 1		15	22	

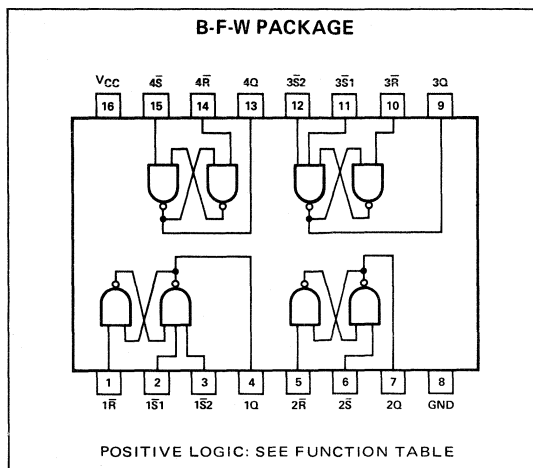
**PARAMETER MEASUREMENT INFORMATION**



### FUNCTION TABLE

INPUTS		OUTPUT
$\bar{S}^*$	$\bar{R}$	Q
H	H	$Q_0$
L	H	H
H	L	L
L	L	$H^1$

### PIN CONFIGURATION



H = high level

L = low level

$Q_0$  = the level of Q before these input conditions were established

\*For latches with double  $\bar{S}$  inputs:

H = both  $\bar{S}$  inputs high

L = one or both  $\bar{S}$  inputs low

<sup>1</sup>This output is pseudo-stable; that is, it may not persist when the  $\bar{S}$  and  $\bar{R}$  inputs return to their inactive (H) level.

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	54279			74279			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from any output, N	High logic level		20			20	
	Low-logic level		10			10	
Operating free-air temperature, $T_A$	-55		125	0		70	$^{\circ}C$

### ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range. Unless otherwise noted.)

PARAMETER	TEST CONDITIONS <sup>1</sup>	MIN	TYP <sup>2</sup>	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MAX}, I_I = -12\text{mA}$			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -800\ \mu\text{A}$	2.4			V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 16\text{mA}$			0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			40	$\mu\text{A}$
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$			-1.6	mA
$I_{OS}$ Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX},$ 54279 74279	-18 -18		-55 -57	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ See Note 1		18	30	mA

Note 1:  $I_{CC}$  is measured with all  $\bar{R}$  inputs grounded, all  $\bar{S}$  inputs at 4.5V, and all outputs open.

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

2. All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^{\circ}C$ .

3. Not more than one output should be shorted at a time.

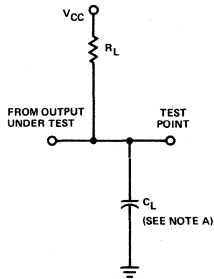
SWITCHING CHARACTERISTICS  $V_{CC} = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ ,  $N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPLH Propagation delay time low-to-high-level output from $\overline{S}$ input	$C_L = 15\text{pF}$ , $R_L = 400\ \Omega$		12	22	
tPHL Propagation delay time, high-to-low-level output from $\overline{S}$			9	15	ns
tPHL Propagation delay time, high-to-low-level output from $\overline{R}$ input			15	27	

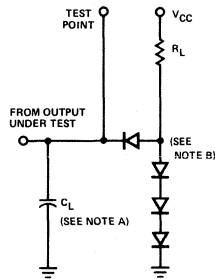
# 54/74 And 54/74H Typical A.C. Loads And Waveforms

## PARAMETER MEASUREMENT INFORMATION

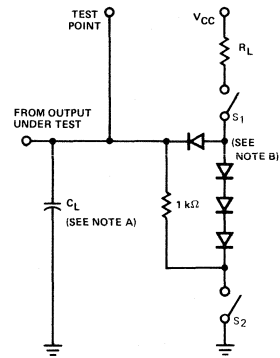
**LOAD CIRCUIT FOR OPEN-COLLECTOR OUTPUTS**



**LOAD CIRCUIT FOR BI-STATE TOTEM-POLE OUTPUTS**



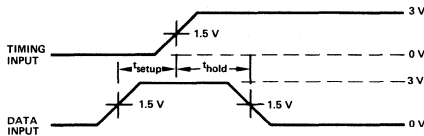
**LOAD CIRCUIT FOR TRI-STATE OUTPUTS**



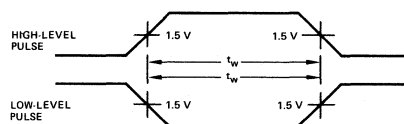
NOTES: A.  $C_L$  includes probe and jig capacitance.  
B. All diodes are 1N3064.

## TYPICAL AC WAVEFORMS

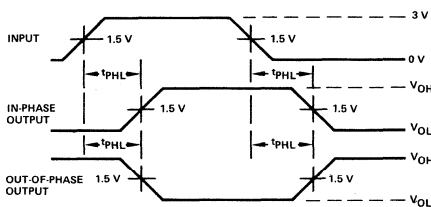
**VOLTAGE WAVEFORMS SETUP AND HOLD TIMES**



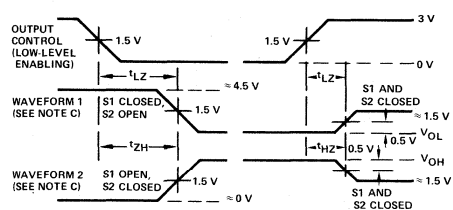
**VOLTAGE WAVEFORMS PULSE WIDTHS**



**VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, TRI-STATE OUTPUTS**

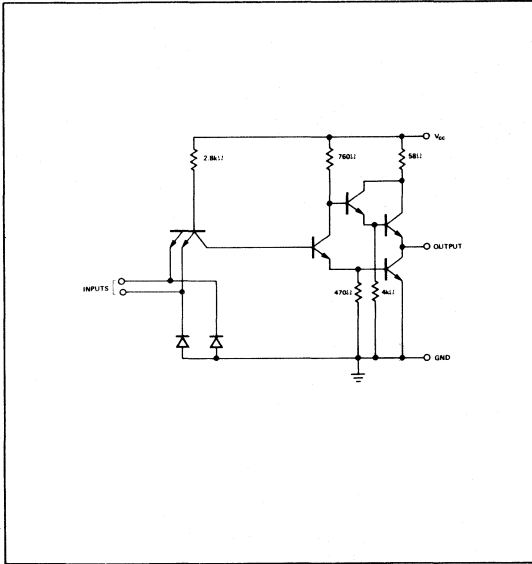


NOTES: C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
D. In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily.  
E. All input pulses are supplied by generators having the following characteristics:  $t_r \leq 2.5$  ns,  $t_f \leq 2.5$  ns,  $PRR \leq 1$  MHz, and  $Z_{out} \approx 50 \Omega$ .

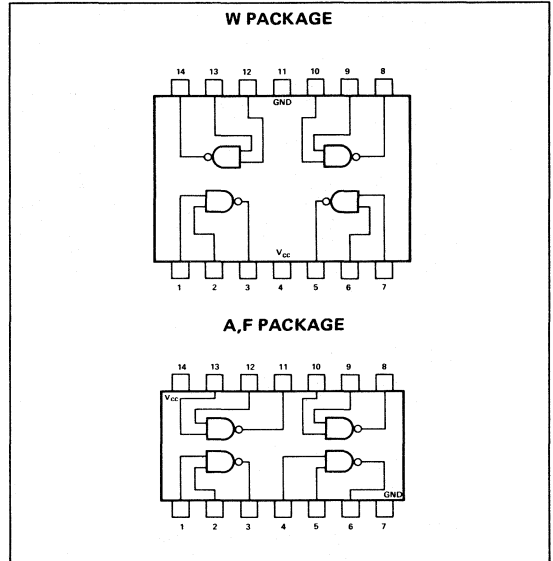
S54H00-A,F,W • N74H00-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATION



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H00 Circuits	4.5	5	5.5	V
N74H00 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H00 Circuits	-55	25	125	$^{\circ}C$
N74H00 Circuits	0	25	70	$^{\circ}C$

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN},$	2		V	
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN},$		0.8	V	
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN},$ $I_{load} = -500\mu A$	$V_{in} = 0.8V,$	2.4	V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN},$ $I_{sink} = 20mA$	$V_{in} = 2V,$	0.4	V	
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$	$V_{in} = 0.4V$	-2	mA	
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$	$V_{in} = 2.4V$ $V_{in} = 5.5V$	50 1	$\mu A$ mA	
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX},$		-40	-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 4.5V$	26	40	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$	10	16.8	mA



## SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND GATE ■ S54H00, N74H00

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		6.2	10	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		5.9	10	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

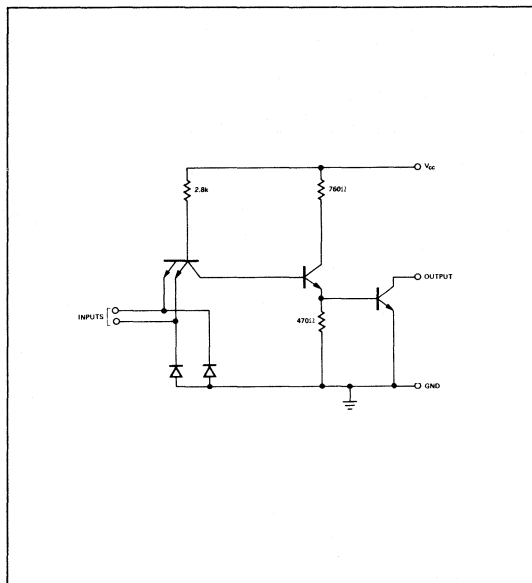
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time, and duration of short circuit test should not exceed 1 second.

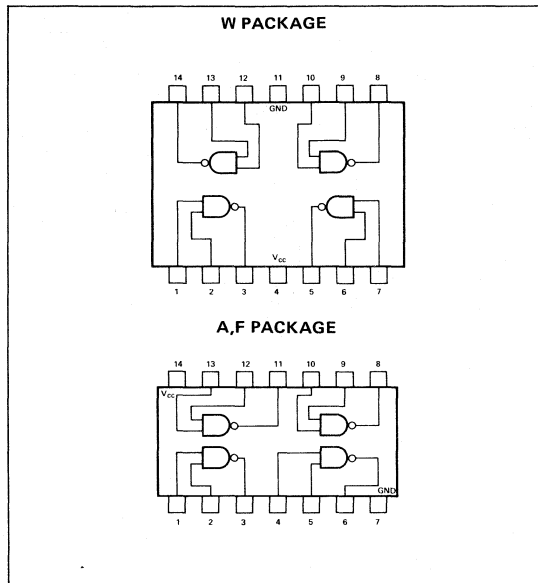
S54H01-A,F,W • N74H01-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H01 Circuits	4.5	5	5.5	V
N74H01 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H01 Circuits	-55	25	125	$^{\circ}$ C
N74H01 Circuits	0	25	70	$^{\circ}$ C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 (on) level at output $V_{CC} = \text{MIN},$	2			V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 (off) level at output $V_{CC} = \text{MIN},$			0.8	V
$I_{out(1)}$	Output reverse current $V_{CC} = \text{MIN},$ $V_{out(1)} = 5.5V$ $V_{in} = 0.8V,$			250	$\mu$ A
$V_{out(0)}$	Logical 0 output voltage (on level) $V_{CC} = \text{MIN},$ $I_{sink} = 20mA$ $V_{in} = 2V,$			0.4	V
$I_{in(0)}$	Logical 0 level input current (each input) $V_{CC} = \text{MAX},$ $V_{in} = 0.4V$			-2	mA
$I_{in(1)}$	Logical 1 level input current (each input) $V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$ $V_{in} = 2.4V$ $V_{in} = 5.5V$			50 1	$\mu$ A mA
$I_{CC(0)}$	Logical 0 level supply current $V_{CC} = \text{MAX},$ $V_{in} = 4.5V$		26	40	mA
$I_{CC(1)}$	Logical 1 level supply current $V_{CC} = \text{MAX}$ $V_{in} = 0$		6.8	10.0	mA

## SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND GATE ■ S54H01, N74H01

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS†		MIN	TYP**	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		7.5	12.0	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		10.0	15.0	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

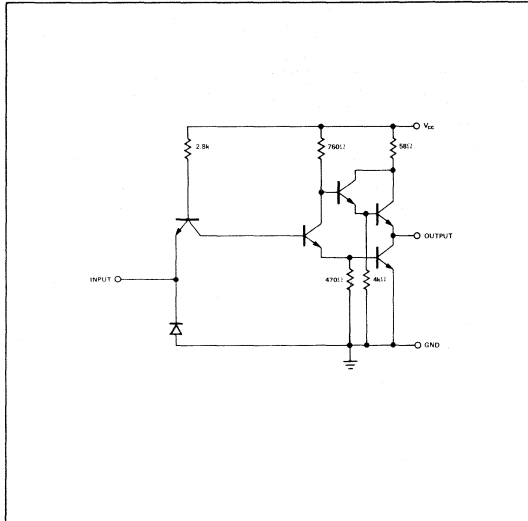
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Load resistor  $R_L$  is connected from  $V_{CC}$  to the output, and load capacitor  $C_L$  is connected from the output to ground.

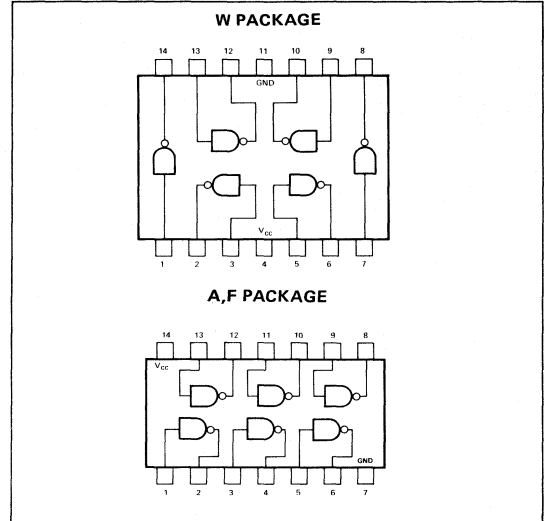
S54H04—A,F,W • N74H04—A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each inverter)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H04 Circuits	4.5	5	5.5	V
N74H04 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H04 Circuits	-55	25	125	°C
N74H04 Circuits	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at input terminal to ensure logical 0 level at output $V_{CC} = \text{MIN}$ ,	2			V
$V_{in(0)}$	Logical 0 input voltage required at input terminal to ensure logical 1 level at output $V_{CC} = \text{MIN}$ ,			0.8	V
$V_{out(1)}$	Logical 1 output voltage $V_{CC} = \text{MIN}$ , $I_{load} = -500\mu A$ , $V_{in} = 0.8V$ ,	2.4			V
$V_{out(0)}$	Logical 0 output voltage $V_{CC} = \text{MIN}$ , $I_{sink} = 20mA$ , $V_{in} = 2V$ ,			0.4	V
$I_{in(0)}$	Logical 0 level input current $V_{CC} = \text{MAX}$ , $V_{in} = 0.4V$			-2	mA
$I_{in(1)}$	Logical 1 level input current $V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4V$ , $V_{in} = 5.5V$			50 1	$\mu A$ mA
$I_{OS}$	Short circuit output current † $V_{CC} = \text{MAX}$ ,	-40		-100	mA
$I_{CC(0)}$	Logical 0 level supply current $V_{CC} = \text{MAX}$ , $V_{in} = 4.5V$ ,		40.0	58.0	mA
$I_{CC(1)}$	Logical 1 level supply current $V_{CC} = \text{MAX}$ , $V_{in} = 0$ ,		16.0	26.0	mA

## SIGNETICS HEX INVERTER ■ S54H04, N74H04

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		6.5	10	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		9.0	13.0	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

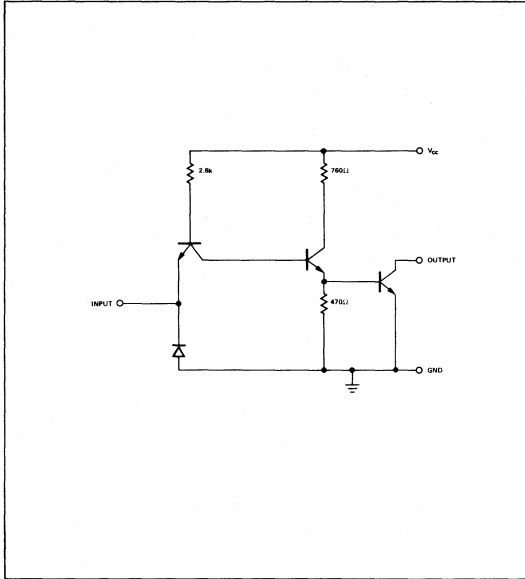
† Not more than one output should be shorted at a time.



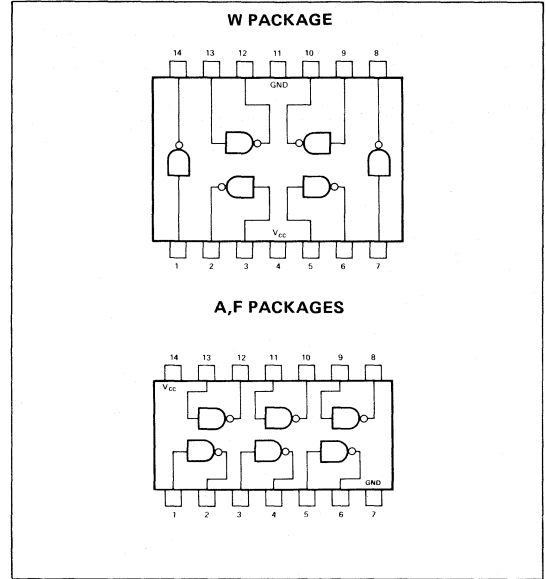
S54H05-A,F,W • N74H05-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each inverter)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :	S54H05 Circuits	4.5	5	5.5	V
	N74H05 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N				10	
Operating Free-Air Temperature Range, $T_A$ :	S54H05 Circuits	-55	25	125	°C
	N74H05 Circuits	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at input terminal to ensure logical 0 (on) level at output	$V_{CC} = \text{MIN}$ ,		2			V
$V_{in(0)}$	Logical 0 input voltage required at input terminal to ensure logical 1 (off) level at output	$V_{CC} = \text{MIN}$ ,				0.8	V
$I_{out(1)}$	Output reverse current	$V_{CC} = \text{MIN}$ , $V_{out(1)} = 5.5\text{V}$	$V_{in} = 0.8\text{V}$ ,			250	$\mu\text{A}$
$V_{out(0)}$	Logical 0 output voltage (on level)	$V_{CC} = \text{MIN}$ , $I_{sink} = 20\text{mA}$	$V_{in} = 2\text{V}$ ,			0.4	V
$I_{in(0)}$	Logical 0 level input current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0.4\text{V}$			-2	mA
$I_{in(1)}$	Logical 1 level input current	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 4.5\text{V}$	40.0		58.0	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$	16.0		26.0	mA

## SIGNETICS HEX INVERTER WITH OPEN COLLECTOR OUTPUT ■ S54H05, N74H05

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

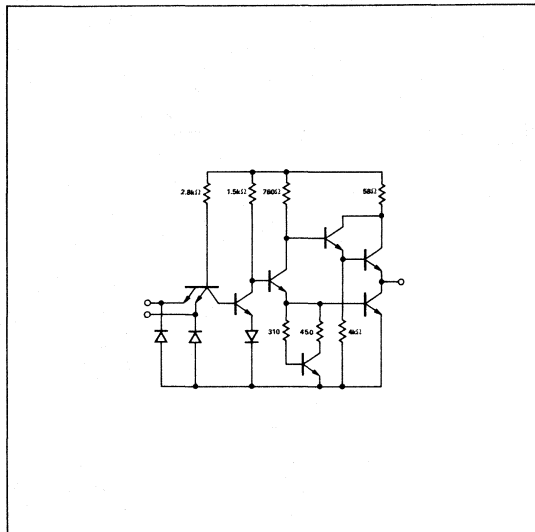
PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		10	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		10	18	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

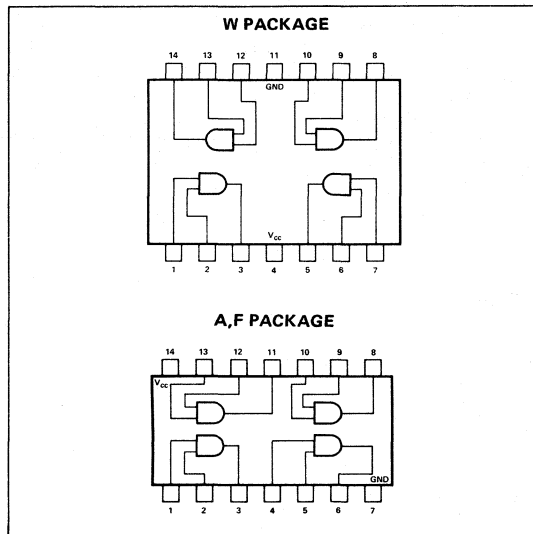
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Load resistor  $R_L$  is connected from  $V_{CC}$  to the output, and load capacitor  $C_L$  is connected from the output to ground.

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :				
S54H08 Circuits	4.5	5	5.5	V
N74H08 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ :				°C
S54H08 Circuits	-55	25	125	
N74H08 Circuits	0	25	70	

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN},$ $V_{out(1)} \geq .4V$	2		V
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN},$ $V_{out(0)} \leq 2.4V$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN},$ $I_{load} = 500\mu A$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN},$ $I_{sink} = 20mA$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{in} = 0.4V$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$ $V_{in} = 2.4V$ $V_{in} = 5.5V$		50 1	$\mu A$ mA
$I_{OS}$	Short-circuit output current †	$V_{CC} = \text{MAX},$	-40	-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 4.5V$	40	64	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 0$	24	40	mA



## SIGNETICS QUADRUPLE 2-INPUT POSITIVE AND GATE ■ S54H08, N74H08

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$V_{CI}$	Input negative clamp voltage	$V_{CC} = 5V$ $T_A = 25^\circ C$	$I_{in} = -12.0mA$			-1.5	V

### SWITCHING CHARACTERISTICS, $V_{CC} = 5V$ , $T_A = 25^\circ C$ , $N = 10$

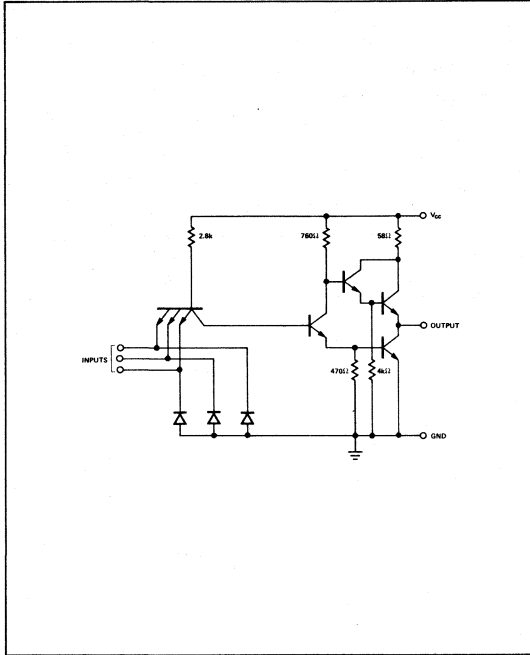
PARAMETER		TEST CONDITIONS		MIN	TYP**	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		8.8	12	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		7.6	12	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

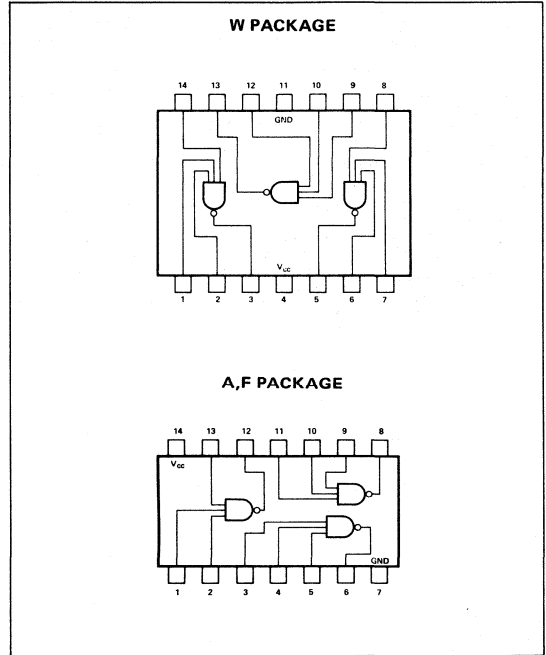
\*\* All typical values at:  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time and duration of short circuit test should not exceed 1 second.

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H10 Circuits	4.5	5	5.5	V
N74H10 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H10 Circuits	-55	25	125	$^{\circ}$ C
N74H10 Circuits	0	25	70	$^{\circ}$ C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$ ,	2		V
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$ ,		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -500\mu\text{A}$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 20\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$		50 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$	-40	-100	mA

## SIGNETICS TRIPLE 3-INPUT POSITIVE NAND GATE ■ S54H10, N74H10

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}, V_{in} = 4.5\text{V}$		19.5	30	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}, V_{in} = 0$		7.5	12.6	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

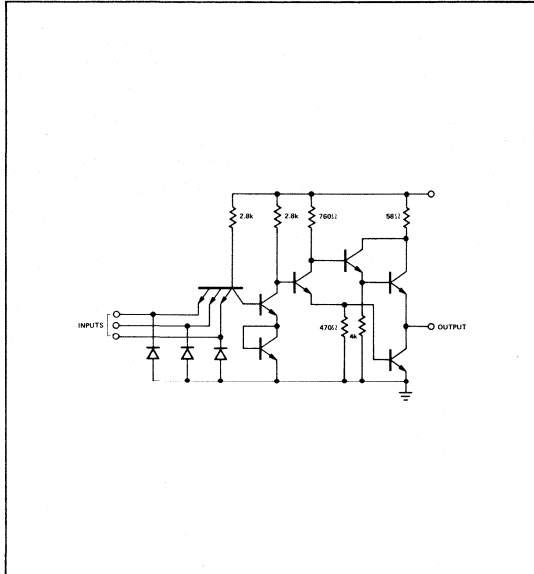
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25\text{pF}, R_L = 280\Omega$		6.3	10	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25\text{pF}, R_L = 280\Omega$		5.9	10	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

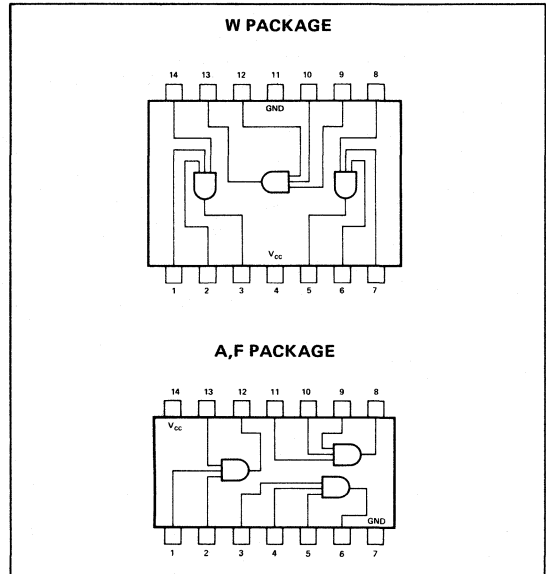
\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time and duration of short circuit test should not exceed 1 second.

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H11 Circuits	4.5	5	5.5	V
N74H11 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H11 Circuits	-55	25	125	$^{\circ}$ C
N74H11 Circuits	0	25	70	$^{\circ}$ C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN},$	2		V
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN},$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ $I_{load} = -500\mu\text{A}$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN},$ $I_{sink} = 20\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$ $V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$		50 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX},$ $V_{in} = 4.5\text{V}$	-40	-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 0$	30	48	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 4.5\text{V}$	18	30	mA

## SIGNETICS TRIPLE 3-INPUT POSITIVE AND GATE ■ S54H11, N74H11

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		8.8	12	ns
$t_{pd1}$	Propagation delay time	$C_L = 25pF$ ,	$R_L = 280\Omega$		7.6	12	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

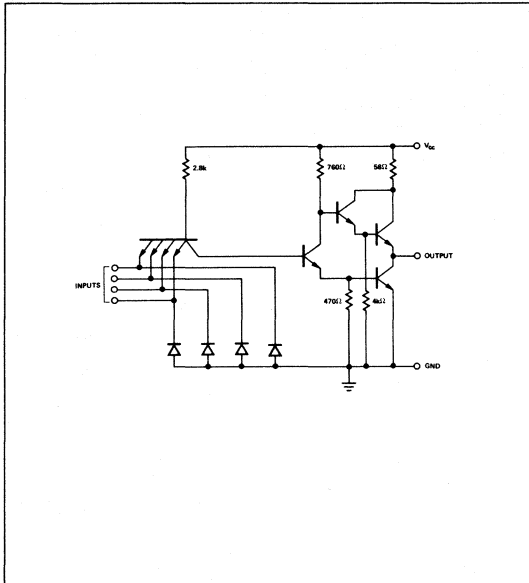
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time and duration of short circuit test should not exceed 1 second.

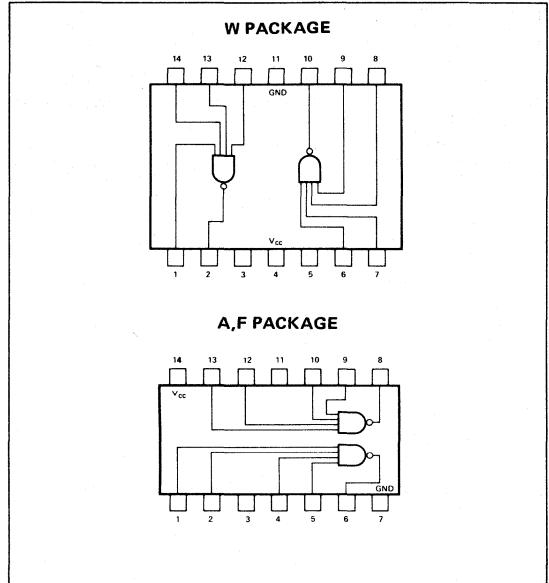
S54H20-A,F,W • N74H20-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H20 Circuits	4.5	5	5.5	V
N74H20 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H20 Circuits	-55	25	125	$^{\circ}$ C
N74H20 Circuits	0	25	70	$^{\circ}$ C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$ ,		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -500\mu\text{A}$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 20\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$		50 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$ ,	-40	-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$	13	20	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	5	8.4	mA

## SIGNETICS DUAL 4-INPUT POSITIVE NAND GATE ■ S54H20, N74H20

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		7	10	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		6	10	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

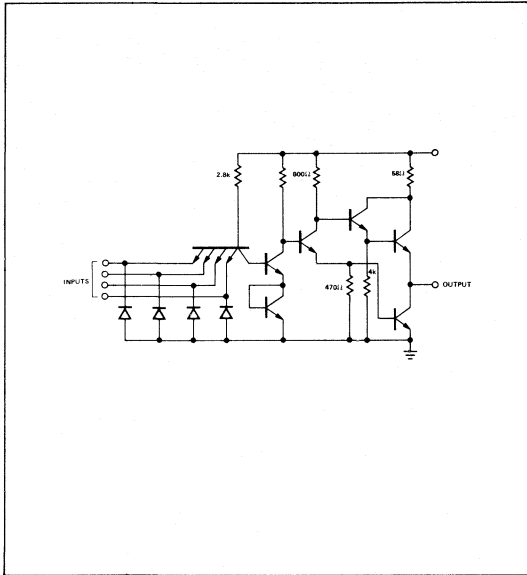
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time and duration of short circuit test should not exceed 1 second.

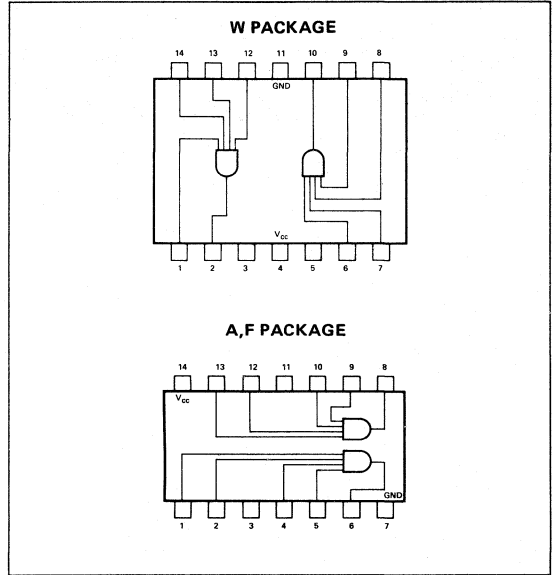
S54H21-A,F,W • N74H21-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H21 Circuits	4.5	5	5.5	V
N74H21 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H21 Circuits	-55	25	125	°C
N74H21 Circuits	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 1 level at output	$V_{CC} = \text{MIN},$	2		V
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 0 level at output	$V_{CC} = \text{MIN},$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN},$ $I_{load} = -500\mu A$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN},$ $I_{sink} = 20\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$	$V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$	50 1	$\mu A$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX},$ $V_{in} = 4.5\text{V}$	-40	-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 0$	20	32	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 4.5\text{V}$	12	20	mA



## SIGNETICS DUAL 4-INPUT POSITIVE AND GATE ■ S54H21, N74H21

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP**	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		8.8	12	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		7.6	12	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

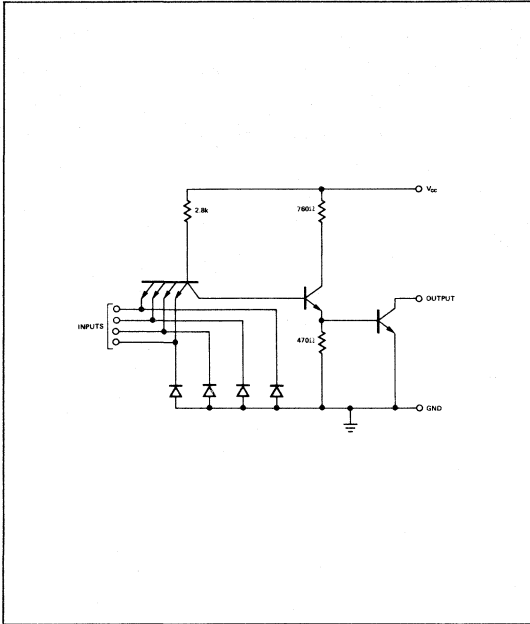
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time and duration of short circuit test should not exceed 1 second.

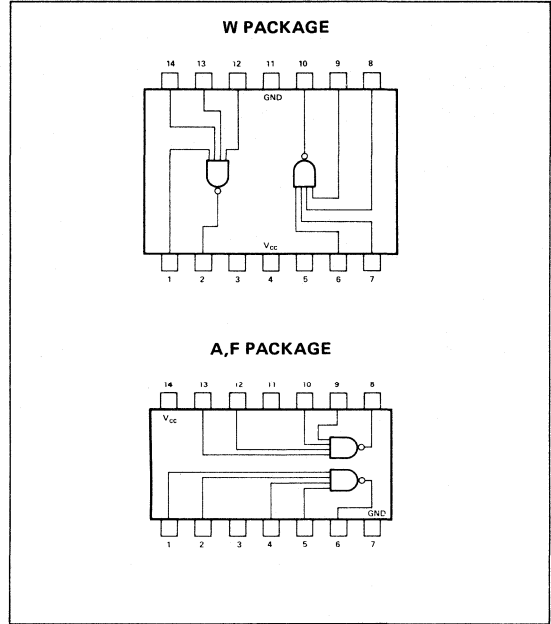
S54H22-A,F,W • N74H22-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER		MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ :	S54H22 Circuits	4.5	5	5.5	V
	N74H22 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N				10	
Operating Free-Air Temperature Range:	S54H22 Circuits	-55	25	125	°C
	N74H22 Circuits	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 (on) level at output	$V_{CC} = \text{MIN},$		2			V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 (off) level at output	$V_{CC} = \text{MIN},$				0.8	V
$I_{out(1)}$	Output reverse current	$V_{CC} = \text{MIN},$ $V_{out(1)} = 5.5V$	$V_{in} = 0.8V$			250	$\mu A$
$V_{out(0)}$	Logical 0 output voltage (on level)	$V_{CC} = \text{MIN},$ $I_{sink} = 20mA$	$V_{in} = 2V,$			0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$	$V_{in} = 0.4V$			-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$	$V_{in} = 2.4V,$ $V_{in} = 5.5V$			50 1	$\mu A$ mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 4.5V$		13	20	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		3.4	5.0	mA

## SIGNETICS DUAL 4-INPUT POSITIVE NAND GATE ■ S54/N74H22

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS†		MIN	TYP**	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		7.5	12.0	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		10.0	15.0	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

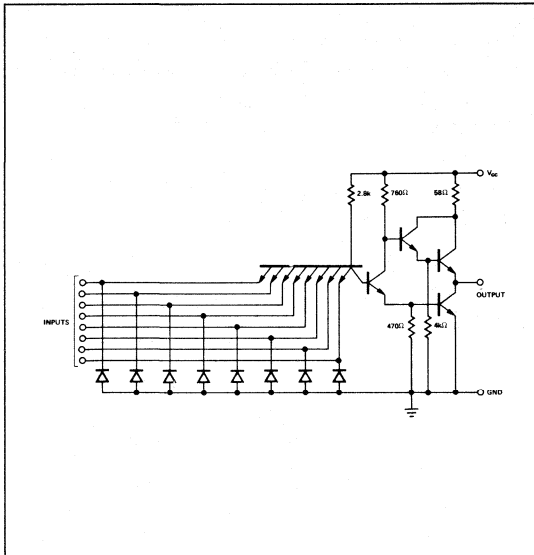
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time and duration of short circuit test should not exceed 1 second.

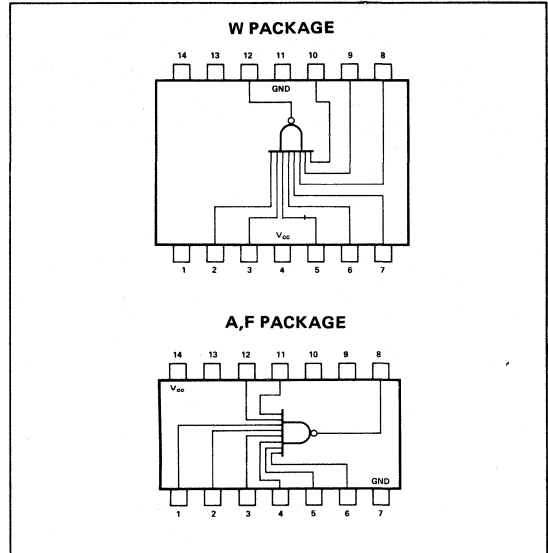
S54H30-A,F,W • N74H30A,F,W

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H30 Circuits N74H30 Circuits	4.5 4.75	5 5	5.5 5.25	V V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H30 Circuits N74H30 Circuits	-55 0	25 25	125 70	°C °C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN}$ ,	2		V
$V_{in(0)}$	Logical 0 input voltage required of any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN}$ ,		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -500\mu A$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 20\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$		50 1	$\mu A$ mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$	-40	-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$	6.5	10	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	2.5	4.2	mA

## SIGNETICS 8-INPUT POSITIVE NAND GATE ■ S54H30, N74H30

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

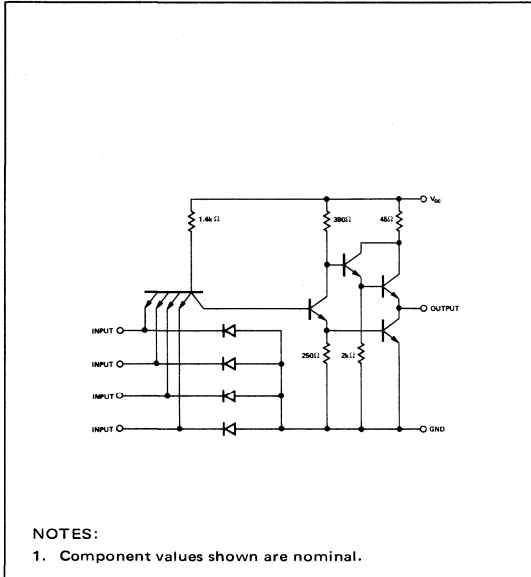
PARAMETER		TEST CONDITIONS		MIN	TYP**	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		8.9	12	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$		6.8	10	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

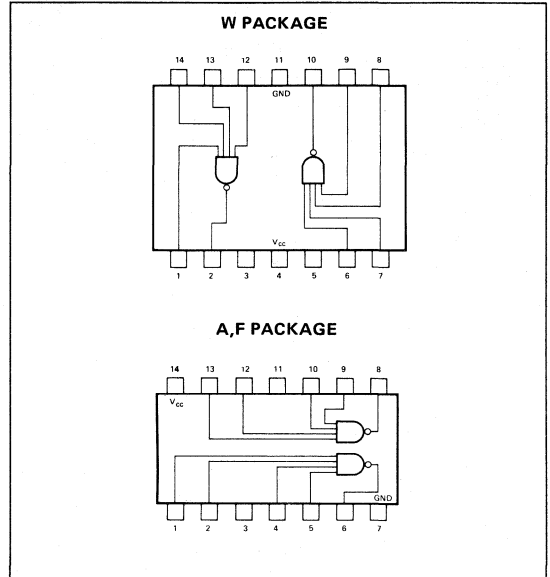
\*\* All typical values at:  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Duration of short circuit test should not exceed 1 second.

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H40 Circuits	4.5	5	5.5	V
N74H40 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			30	
Operating Free-Air Temperature Range, $T_A$ : S54H40 Circuits	-55	25	125	$^{\circ}C$
N74H40 Circuits	0	25	70	$^{\circ}C$

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure logical 0 level at output	$V_{CC} = \text{MIN},$	2		V
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure logical 1 level at output	$V_{CC} = \text{MIN},$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN},$ $I_{load} = -1.5\text{mA}$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN},$ $I_{sink} = 60\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{in} = 0.4\text{V}$		-4	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$ $V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$		100 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current**	$V_{CC} = \text{MAX}$	-40	-125	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 4.5\text{V}$	25	40	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$ $V_{in} = 0$	10.4	16	mA

# SIGNETICS DUAL 4-INPUT POSITIVE NAND BUFFER ■ S54H40, N74H40

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 30$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 93\Omega$		6.5	12	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 93\Omega$		8.5	12	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

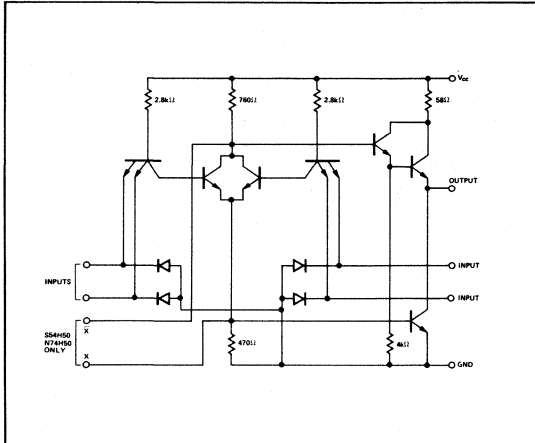
\*\* Not more than one output should be shorted at a time, and duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

S54H50-A,F,W • S54H51-A,F,W • N74H50-A,F • N74H51-A,F

DIGITAL 54/74 TTL SERIES

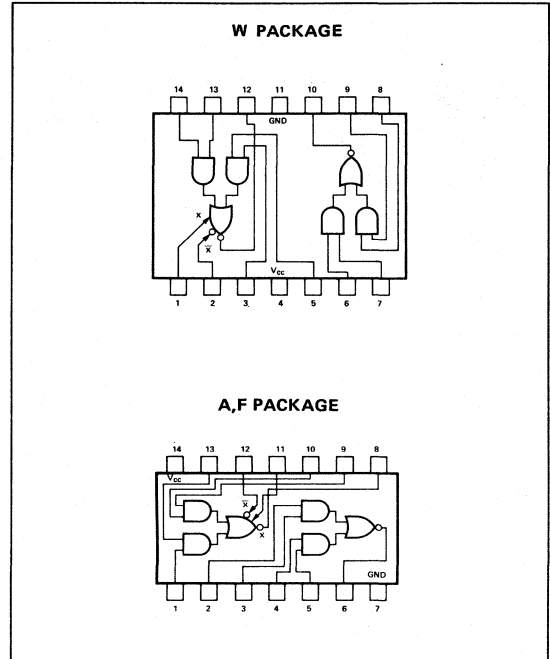
#### SCHEMATIC (each gate)



#### NOTES:

1. Component values are nominal.
2. Both expander inputs are used simultaneously for expanding.
3. If expander is not used leave X and X pins open.
4. Expander inputs X and X are functional on the S54H50 and N74H50 circuits only. Make no external connection to X and X pins of the S54H51 and N74H51.
5. A total of four S54H60/N74H60 expander gates or one S54H62/N74H62 expander gate may be connected to the expander inputs.

#### PIN CONFIGURATIONS



#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H50, S54H51 Circuits	4.5	5	5.5	V
N74H50, N74H51 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H50, S54H51 Circuits	-55	25	125	$^{\circ}$ C
N74H50, N74H51 Circuits	0	25	70	$^{\circ}$ C

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at both input terminals of either AND section to ensure logical 0 at output	$V_{CC} = \text{MIN}$		2	V
$V_{in(0)}$	Logical 0 input voltage required at one input terminal of each AND section to ensure logical 1 at output	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -500\mu\text{A}$	$V_{in} = 0.8\text{V}$ ,	2.4	V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 20\text{mA}$	$V_{in} = 2\text{V}$ ,	0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$		50 1	$\mu\text{A}$ mA



# SIGNETICS DUAL 2-WIDE 2-INPUT AND-OR-INVERT GATES ■ S54H50, S54H51, N74H50, N74H51

## ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{OS}$	Short circuit output current**	$V_{CC} = \text{MAX}$	-40		-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}, V_{in} = 4.5V$		15.2	24	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}, V_{in} = 0$		8.2	12.8	mA

## ELECTRICAL CHARACTERISTICS (S54H50 circuits only) using expander inputs, $V_{CC} = 4.5V, T_A = -55^\circ C$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{in\bar{X}}$	Expander-node input current	$V_{\bar{X}} = 1.4V$			-5.85	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor Q	$I_{sink} = 20mA, I_1 = 700\mu A, R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -500\mu A, I_1 = 320\mu A, I_2 = -320\mu A$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 20mA, I_1 = 470\mu A, R_1 = 68\Omega$			0.4	V

## ELECTRICAL CHARACTERISTICS (N74H50 circuits only) using expander inputs, $V_{CC} = 4.5V, T_A = 0^\circ C$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{in\bar{X}}$	Expander-node input current	$V_{\bar{X}} = 1.4V$			-6.3	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor Q	$I_{sink} = 20mA, I_1 = 1.1mA, R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -500\mu A, I_1 = 570\mu A, I_2 = -570\mu A$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 20mA, I_1 = 600\mu A, R_1 = 63\Omega$			0.4	V

## SWITCHING CHARACTERISTICS, $V_{CC} = 5V, T_A = 25^\circ C, N = 10$ , expander pins are open

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF, R_L = 280\Omega$		6.2	11	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF, R_L = 280\Omega$		6.8	11	ns

## SWITCHING CHARACTERISTICS, (S54H50/N74H50 circuits only), $V_{CC} = 5V, T_A = 25^\circ C, N = 10, C_X = 15 pF$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF, R_L = 280\Omega$		7.4		ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF, R_L = 280\Omega$		11		ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander pins are open.

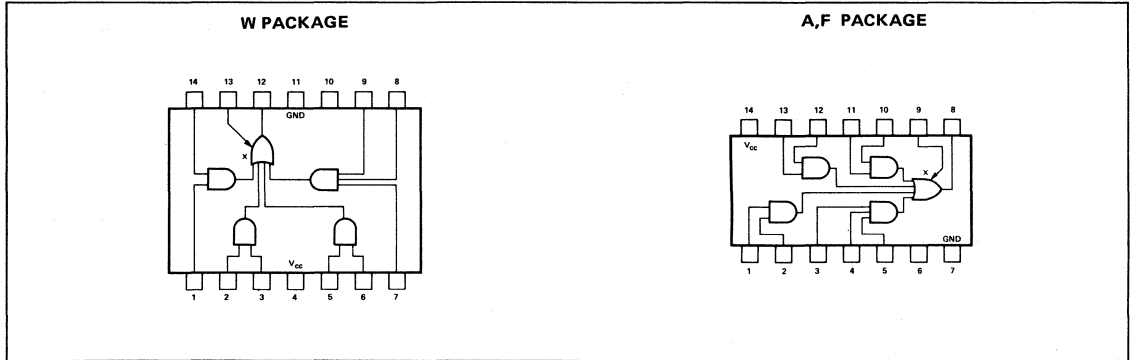
\*\* Not more than one output should be shorted at a time, and duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

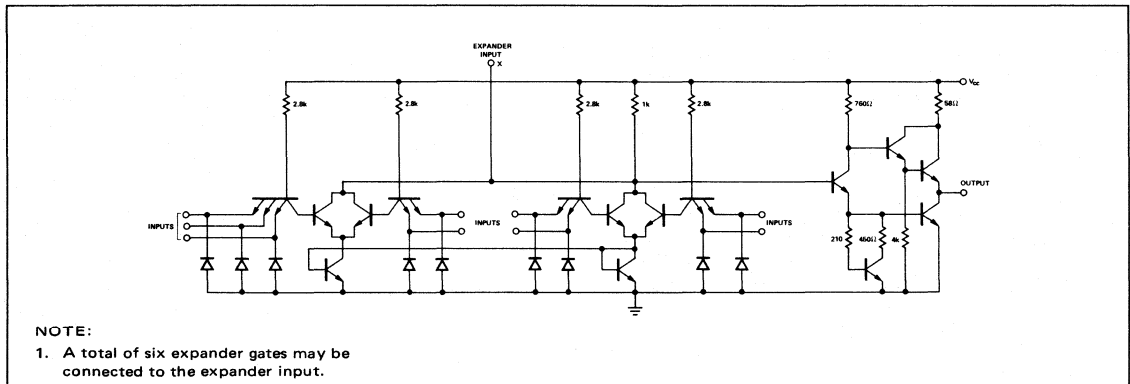
S54H52-A,F,W • N74H52-A,F

DIGITAL 54/74 TTL SERIES

### PIN CONFIGURATIONS



### SCHEMATIC DIAGRAM



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H52 Circuits	4.5	5	5.5	V
N74H52 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H52 Circuits	-55	25	125	°C
N74H52 Circuits	0	25	70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals of one AND section to ensure logical 1 at output	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Logical 0 input voltage required at one input terminal of each AND section to ensure logical 0 at output	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -500\mu\text{A}$	$V_{in} = 2\text{V}$ ,	2.4	V

## SIGNETICS 4-WIDE 2-2-2-3-INPUT AND-OR GATE ■ S54H52, N74H52

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN},$ $I_{\text{sink}} = 20\text{mA}$	$V_{in} = 0.8\text{V},$			0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$	$V_{in} = 0.4\text{V}$			-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{CC} = \text{MAX},$	$V_{in} = 2.4\text{V}$ $V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current**	$V_{CC} = \text{MAX},$	$V_{in} = 4.5\text{V}$	-40		-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 0$		15.2	24	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX},$	$V_{in} = 4.5\text{V}$		20	31	mA

### ELECTRICAL CHARACTERISTICS (S54H52 circuits only) using expander input, $V_{CC} = 4.5\text{V}$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{inX}$	Expander-node input current	$V_X = 1\text{V},$ $T_A = -55^\circ\text{C}$	$I_{load} = -500\mu\text{A},$	-2.7		-4.5	mA
$V_{out(1)}$	Logical 1 output voltage	$V_X = 1\text{V},$ $T_A = -55^\circ\text{C}$	$I_{load} = -500\mu\text{A},$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{inX} = -300\mu\text{A},$ $T_A = 125^\circ\text{C}$	$I_{\text{sink}} = 20\text{mA},$			0.4	V

### ELECTRICAL CHARACTERISTICS (N74H52 circuits only) using expander input, $V_{CC} = 4.75\text{V}$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{inX}$	Expander-node input current	$V_X = 1\text{V},$	$I_{load} = -500\mu\text{A},$ $T_A = 0^\circ\text{C}$	-2.9		-5.35	mA
$V_{out(1)}$	Logical 1 output voltage	$V_X = 1\text{V},$	$I_{load} = -500\mu\text{A},$ $T_A = 0^\circ\text{C}$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{inX} = -300\mu\text{A},$	$I_{\text{sink}} = 20\text{mA},$ $T_A = 70^\circ\text{C}$			0.4	V

### SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10,$ expander pin is open

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25\text{pF},$	$R_L = 280\Omega$		9.2	15	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25\text{pF},$	$R_L = 280\Omega$		10.6	15	ns

### SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10, C_X = 15\text{pF}$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25\text{pF},$	$R_L = 280\Omega$		9.8		ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25\text{pF},$	$R_L = 280\Omega$		14.8		ns

\* For conditions shown as MIN or MAX, use the appropriate values specified under recommended operating conditions for the applicable device type. Expander pin is open.

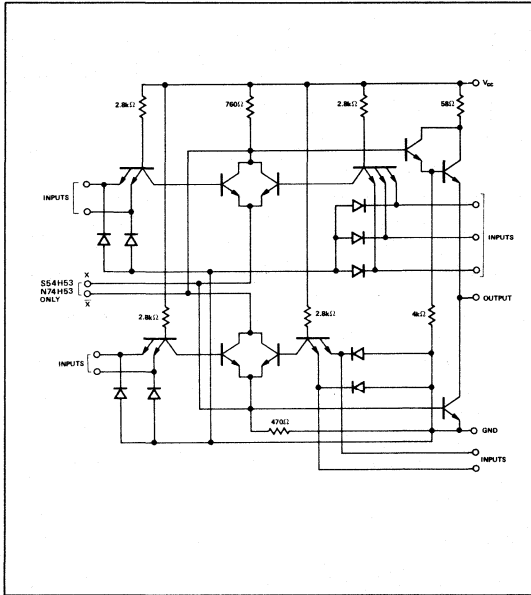
\*\* Duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}.$

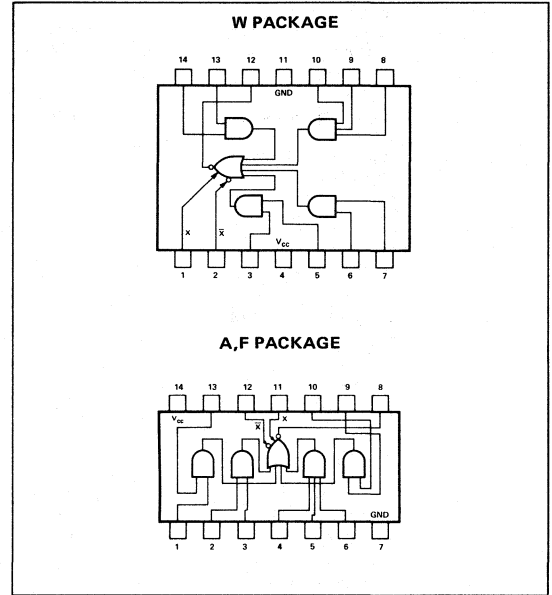
S54H53—A,F,W • S54H54—A,F,W • N74H53—A,F • N74H54—A,F

DIGITAL 54/74 TTL SERIES

#### SCHEMATIC DIAGRAM



#### PIN CONFIGURATIONS



#### NOTES:

1. Component values shown are nominal.
2. Both expander inputs are used simultaneously for expanding.
3. If expander is not used leave X and  $\bar{X}$  pins open.
4. Expander inputs X and  $\bar{X}$  are functional on the S54H53 and N74H53 circuits only.

5. A total of four S54H60/N74H60 expander gates or one S54H62/N74H62 expander gate may be connected to the expander inputs.

#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H53, S54H54 Circuits	4.5	5	5.5	V
N74H53, N74H54 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H53, S54H54 Circuits	-55	25	125	°C
N74H53, N74H54 Circuits	0	25	70	°C

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at all input terminals of one AND section to ensure logical 0 at output	$V_{CC} = \text{MIN},$	2			V
$V_{in(0)}$ Logical 0 input voltage required at one input terminal of each AND section to ensure logical 1 at output	$V_{CC} = \text{MIN},$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ $I_{load} = -500\mu\text{A}$ $V_{in} = 0.8\text{V},$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ $I_{sink} = 20\text{mA}$ $V_{in} = 2\text{V},$			0.4	V
$I_{in(0)}$ Logical 0 level input current (each input)	$V_{CC} = \text{MAX},$ $V_{in} = 0.4\text{V}$			-2	mA

## SIGNETICS EXPANDABLE GATE ■ S54H53, S54H54, N74H53, N74H54

### ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_{in} = 2.4\text{V}$				50	$\mu\text{A}$
$I_{OS}$	Short circuit output current**	$V_{CC} = \text{MAX}$ ,	$V_{in} = 5.5\text{V}$		-40		1	$\text{mA}$
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 4.5\text{V}$			9.4	14	$\text{mA}$
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ ,	$V_{in} = 0$			7.1	11	$\text{mA}$

### ELECTRICAL CHARACTERISTICS (S54H53 circuits only) using expander inputs, $V_{CC} = 4.5\text{V}$ , $T_A = -55^\circ\text{C}$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{in\bar{X}}$	Expander-node input current	$V_{\bar{X}} = 1.4\text{V}$					-5.85	$\text{mA}$
$V_{BE(Q)}$	Base-emitter voltage of output transistor Q	$I_{\text{sink}} = 20\text{mA}$ ,	$I_1 = 700\mu\text{A}$ ,	$R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{\text{load}} = -500\mu\text{A}$ ,	$I_1 = 320\mu\text{A}$ ,		2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{\text{sink}} = 20\text{mA}$	$I_1 = 470\mu\text{A}$ ,	$R_1 = 68\Omega$			0.4	V

### ELECTRICAL CHARACTERISTICS (N74H53 circuits only) using expander inputs, $V_{CC} = 4.75\text{V}$ , $T_A = 0^\circ\text{C}$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{in\bar{X}}$	Expander-node input current	$V_{\bar{X}} = 1.4\text{V}$					-6.3	$\text{mA}$
$V_{BE(Q)}$	Base-emitter voltage of output transistor Q	$I_{\text{sink}} = 20\text{mA}$ ,	$I_1 = 1.1\text{mA}$ ,	$R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{\text{load}} = -500\mu\text{A}$ ,	$I_1 = 570\mu\text{A}$ ,		2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{\text{sink}} = 20\text{mA}$ ,	$I_1 = 600\mu\text{A}$ ,	$R_1 = 63\Omega$			0.4	V

### SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , $N = 10$ , expander pins are open

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25\text{pF}$ ,	$R_L = 280\Omega$			6.2	11	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25\text{pF}$ ,	$R_L = 280\Omega$			7	11	ns

### SWITCHING CHARACTERISTICS, (S54H53/N74H53 circuits only) $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , $N = 10$ , $C_X = 15\text{pF}$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25\text{pF}$ ,	$R_L = 280\Omega$			7.4		ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25\text{pF}$ ,	$R_L = 280\Omega$			11.4		ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander pins are open.

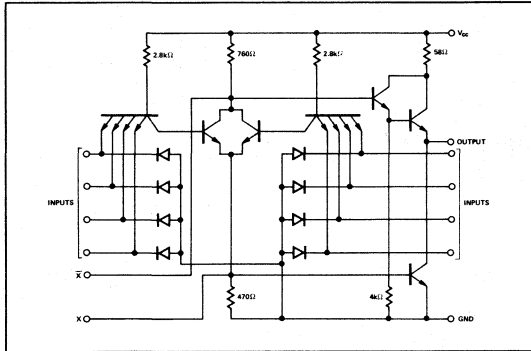
\*\* Duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

S54H55-A,F,W • N74H55-A,F

### DIGITAL 54/74 TTL SERIES

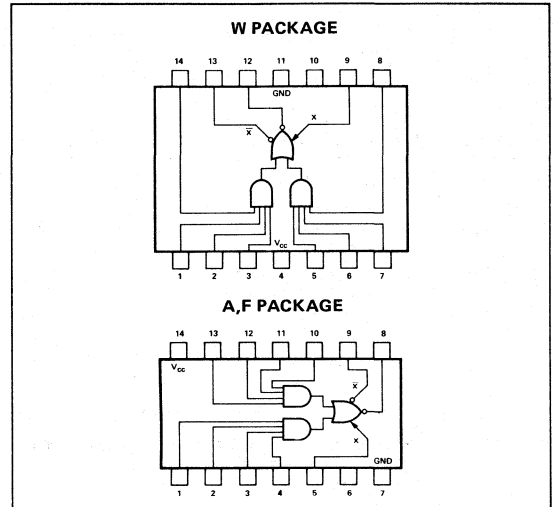
#### SCHEMATIC DIAGRAM



#### NOTES:

1. Component values shown are nominal.
2. Both expander inputs are used simultaneously for expanding.
3. If expander is not used, leave X and X pins open.
4. A total of four S54H60/N74H60 expander gates or one S54H62/N74H62 expander gate may be connected to the expander inputs.

#### PIN CONFIGURATIONS



#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H55 Circuits	4.5	5	5.5	V
N74H55 Circuits	4.75	5	5.25	V
Normalized Fan-Out from each Output, N			10	
Operating Free-Air Temperature Range, $T_A$ : S54H55 Circuits	-55	25	125	$^{\circ}$ C
N74H55 Circuits	0	25	70	$^{\circ}$ C

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*		MIN	TYP†	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals of either AND section to ensure logical 0 at output	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$	Logical 0 input voltage required at one input terminal of each AND section to ensure logical 1 at output	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = -500\mu\text{A}$	2.4			V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 20\text{mA}$			0.4	V
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}$ , $V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ , $V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current**	$V_{CC} = \text{MAX}$	-40		-100	mA
$I_{CC(0)}$	Logical 0 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$		7.5	12	mA
$I_{CC(1)}$	Logical 1 level supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 0$		4.5	6.4	mA

## SIGNETICS EXAPNDABLE 4-INPUT AND-OR-INVERT GATES ■ S54H55, N74H55

ELECTRICAL CHARACTERISTICS (S54H55 circuits only) using expander inputs,  $V_{CC} = 4.5V$ ,  $T_A = -55^\circ C$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{in\bar{X}}$	Expander-node input current	$V_{\bar{X}} = 1.4V$					-5.85	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor Q	$I_{sink} = 20mA$ ,	$I_1 = 700\mu A$ ,	$R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -500\mu A$ , $I_2 = -320\mu A$	$I_1 = 320\mu A$ ,		2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 20mA$ ,	$I_1 = 470\mu A$ ,	$R_1 = 68\Omega$			0.4	V

ELECTRICAL CHARACTERISTICS (N74H55 circuits only) using expander inputs,  $V_{CC} = 4.75V$ ,  $T_A = 0^\circ C$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$I_{in\bar{X}}$	Expander-node input current	$V_{\bar{X}} = 1.4V$					-6.3	mA
$V_{BE(Q)}$	Base-emitter voltage of output transistor Q	$I_{sink} = 20mA$ ,	$I_1 = 1.1mA$ ,	$R_1 = 0$			1	V
$V_{out(1)}$	Logical 1 output voltage	$I_{load} = -500\mu A$ , $I_2 = -570\mu A$	$I_1 = 570\mu A$ ,		2.4			V
$V_{out(0)}$	Logical 0 output voltage	$I_{sink} = 20mA$ ,	$I_1 = 600\mu A$ ,	$R_1 = 63\Omega$			0.4	V

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$ , expander pins are open

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$			6.5	11	ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$			7	11	ns

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$ ,  $C_X = 15pF$

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$t_{pd0}$	Propagation delay time to logical 0 level	$C_L = 25pF$ ,	$R_L = 280\Omega$			7.7		ns
$t_{pd1}$	Propagation delay time to logical 1 level	$C_L = 25pF$ ,	$R_L = 280\Omega$			11.4		ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander pins are open.

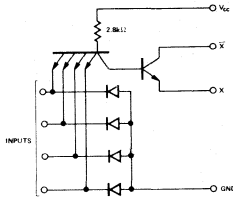
\*\* Duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

S54H60-A,F,W

DIGITAL 54/74 TTL SERIES

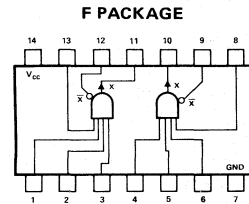
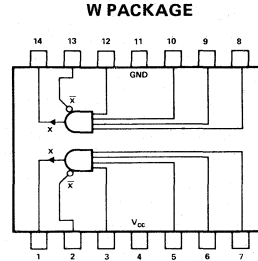
### SCHEMATIC (each expander)



#### NOTES:

1. Connect to X input of S54H50, S54H53, or S54H55 circuit.
2. Connect to  $\bar{X}$  input of S54H50, S54H53, or S54H55 circuit.
3. Component values shown are nominal.

### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

Supply Voltage $V_{CC}$	4.5V to 5.5V
Maximum number of expanders that may be fanned-in to one S54H50, S54H53, or S54H55 circuit	4

### ELECTRICAL CHARACTERISTICS (unless otherwise noted $T_A = -55^\circ\text{C}$ to $125^\circ\text{C}$ )

PARAMETER	TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure output is in the on state	$V_{CC} = 4.5V$	2		V	
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure output is in the off state	$V_{CC} = 4.5V$		0.8	V	
$V_{on}$	On-state output voltage	$V_{CC} = 4.5V,$ $I_{on} = 5.85mA,$ $V_{CC} = 5.5V,$ $I_{on} = 7.85mA,$	$V_{in} = 2V,$ $T_A = -55^\circ$	$V_1 = 1V,$	0.4	V
$I_{off}$	Off-state output current	$V_{CC} = 4.5V,$ $R = 575\Omega,$	$V_{in} = 0.8V,$ $T_A = -55^\circ\text{C}$	$V_1 = 4.5V,$	320	$\mu\text{A}$
$I_{on}$	On-state output current	$V_{CC} = 4.5V,$ $T_A = -55^\circ\text{C}$	$V_{in} = 2V,$	$V_1 = 1V,$	-470	$\mu\text{A}$
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = 5.5V$	$V_{in} = 0.4V$		-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = 5.5V,$ $V_{CC} = 5.5V,$	$V_{in} = 2.4V$ $V_{in} = 5.5V$		50 1	$\mu\text{A}$ mA
$I_{CC(on)}$	On-state supply current	$V_{CC} = 5.5V,$ $V_1 = 0.85V$	$V_{in} = 4.5V,$		1.9 3.5	mA
$I_{CC(off)}$	Off-state supply current	$V_{CC} = 5.5V,$ $V_1 = 0.85V$	$V_{in} = 0,$		3 4.5	mA

<sup>†</sup> All typical values are at  $V_{CC} = 5V, T_A = 25^\circ\text{C}.$



# SIGNETICS DUAL 4-INPUT EXPANDER ■ S54H60

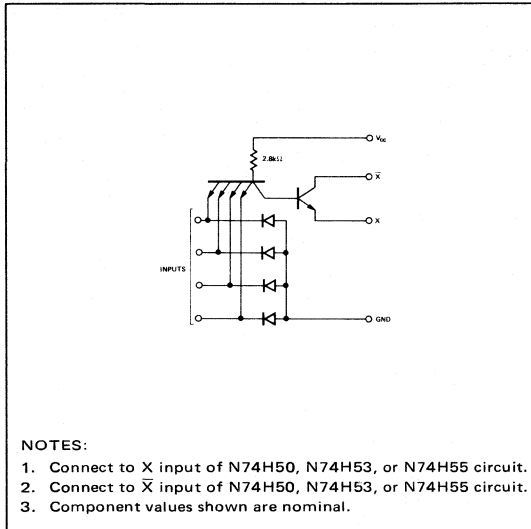
OUTPUT CAPACITANCE  $V_{CC}$  and GND terminals open,  $T_A = 25^\circ\text{C}$ .

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_X$	Effective capacitance of output transistor $Q_1$	$f = 1\text{ MHz}$		1.3		$\mu\text{F}$

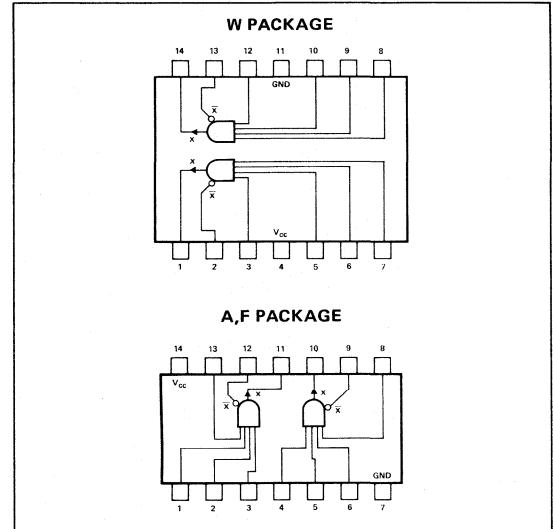
N74H60-A,F

DIGITAL 54/74 TTL SERIES

### SCHEMATIC (each expander)



### PIN CONFIGURATIONS



### RECOMMENDED OPERATING CONDITIONS

Supply Voltage $V_{CC}$	4.75V to 5.25V
Maximum number of expanders that may be fanned-in to one N74H50, N74H53, or N74H55 circuit	4

### ELECTRICAL CHARACTERISTICS (unless otherwise noted $T_A = 0^\circ\text{C}$ to $70^\circ\text{C}$ )

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure output is in the on state	$V_{CC} = 4.75V$		2	V	
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure output is in the off state	$V_{CC} = 4.75V$		0.8	V	
$V_{OS}$	On-state output voltage	$V_{CC} = 4.75V, I_{on} = 6.3mA, T_A = 0^\circ\text{C}$	$V_{in} = 2V, V_1 = 1V, T_A = 0^\circ\text{C}$	0.4	V	
		$V_{CC} = 5.25V, I_{on} = 7.4mA, T_A = 70^\circ\text{C}$	$V_{in} = 2V, V_1 = 0.6V, T_A = 70^\circ\text{C}$	0.4	V	
$I_{off}$	Off-state output current	$V_{CC} = 4.75V, R = 575\Omega$	$V_{in} = 0.8V, T_A = 0^\circ\text{C}$	570	$\mu A$	
$I_{on}$	On-state output current	$V_{CC} = 4.75V, T_A = 0^\circ\text{C}$	$V_{in} = 2V, V_1 = 1V$	-600	$\mu A$	
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = 5.25V$	$V_{in} = 0.4V$	-2	mA	
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = 5.25V$	$V_{in} = 2.4V$	50	$\mu A$	
		$V_{CC} = 5.25V$	$V_{in} = 5.5V$	1	mA	
$I_{CC(on)}$	On-state supply current	$V_{CC} = 5.25V, V_1 = 0.85V$	$V_{in} = 4.5V$	1.9	3.5	mA
$I_{CC(off)}$	Off-state supply current	$V_{CC} = 5.25V, V_1 = 0.85V$	$V_{in} = 0$	3	4.5	mA

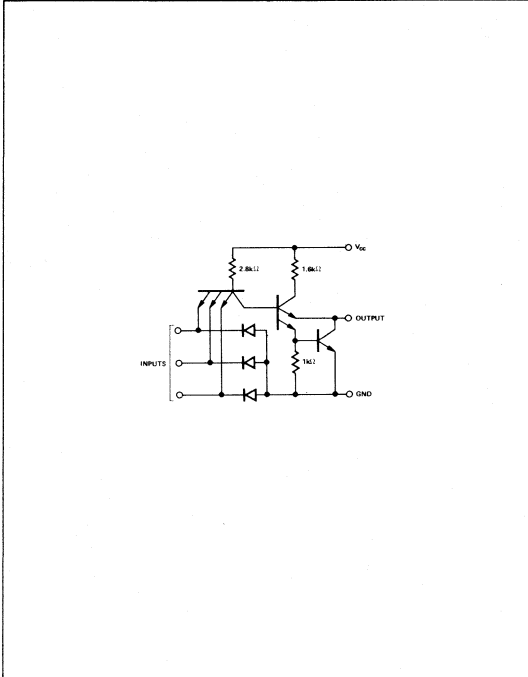
SIGNETICS DUAL 4-INPUT EXPANDER ■ N74H60

OUTPUT CAPACITANCE  $V_{CC}$  and GND terminals open,  $T_A = 25^\circ C$

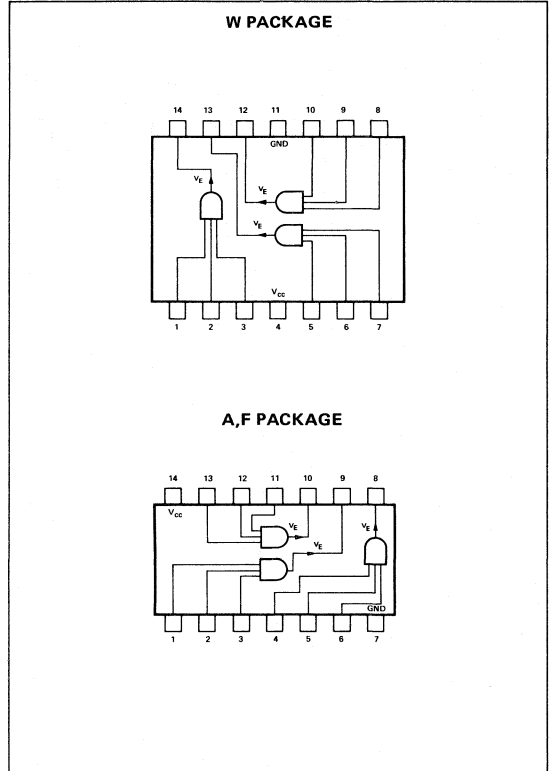
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Cx	Effective capacitance of output transistor $Q_1$	f = 1 MHz		1.3		pF

† All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

SCHEMATIC (each expander)



PIN CONFIGURATIONS



NOTES:

- Component values shown are nominal.
- A total of six expander gates may be connected to the S54H52/N74H52 expander input.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H61 Circuits	4.5	5	5.5	V
N74H61 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H61 Circuits	-55	25	125	°C
N74H61 Circuits	0	25	70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT	
$V_{in(0)}$	Logical 0 input voltage required at any input terminal to ensure output is in the off state	$V_{CC} = \text{MIN}$			0.8	V
$I_{off}$	Off-state reverse current	$V_{CC} = \text{MIN}, V_{off} = 2.2V, T_A = \text{MAX}$		50	$\mu A$	
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 0.4V$		-2	mA	
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = \text{MAX}, V_{in} = 2.4V$		50	$\mu A$	
		$V_{CC} = \text{MAX}, V_{in} = 5.5V$		1	mA	
$I_{CC(on)}$	On-state supply current	$V_{CC} = \text{MAX}, V_{in} = 4.5V$		11	mA	
$I_{CC(off)}$	Off-state supply current	$V_{CC} = \text{MAX}, V_{in} = 0$		5	mA	

## SIGNETICS TRIPLE 3-INPUT EXPANDER ■ S54H61, N74H61

### ELECTRICAL CHARACTERISTICS S54H61 circuits only

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure output is in the on state	$V_{CC} = 4.5V$	2			V
$V_{on}$	On-state output voltage	$V_{CC} = 4.5V,$ $I_{on} = 4.5mA,$			1	V
		$V_{in(1)} = 2V,$ $T_A = -55^{\circ}C$				

### ELECTRICAL CHARACTERISTICS N74H61 circuits only

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals to ensure output is in the on state	$V_{CC} = 4.75V$	2			V
$V_{on}$	On-state output voltage	$V_{CC} = 4.75V,$ $I_{on} = 5.35mA,$			1	V
		$V_{in(1)} = 2V,$ $T_A = 0^{\circ}C$				

### OUTPUT CAPACITANCE, $V_{CC}$ and GND terminals open, $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_x$	Effective capacitance of output transistor $Q_1$	$f = 1\text{ MHz}$		1.3		pF

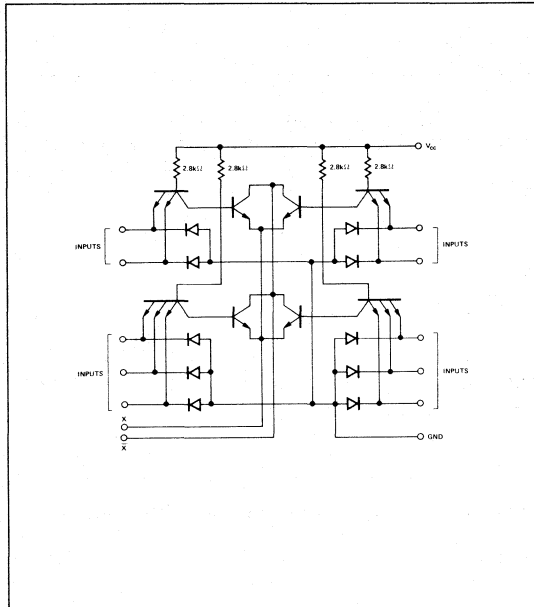
\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

† All typical values are at  $V_{CC} = 5V, T_A = 25^{\circ}C$

S54H62-A,F,W

DIGITAL 54/74 TTL SERIES

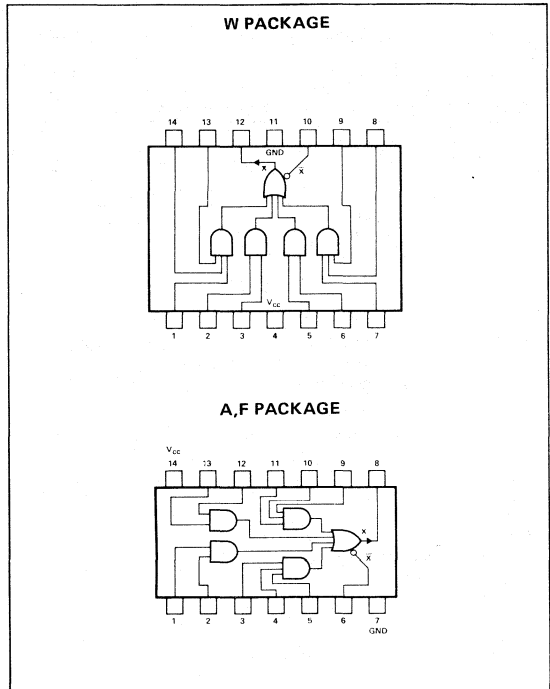
**SCHEMATIC (each gate)**



**NOTES:**

1. Connect to X input of S54H50, S54H53, or S54H55 circuit
2. Connect to  $\bar{X}$  input of S54H50, S54H53, or S54H55 circuit
3. Component values shown are nominal.

**PIN CONFIGURATIONS**



**RECOMMENDED OPERATING CONDITIONS**

Supply Voltage $V_{CC}$	4.5V to 5.5V
Maximum number of expanders that may be fanned-in to one S54H50, S54H53, or S54H55 circuit	1

**ELECTRICAL CHARACTERISTICS (unless otherwise noted  $T_A = -55^\circ\text{C}$  to  $125^\circ\text{C}$ )**

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals of one AND section to ensure output is in the on state	$V_{CC} = 4.5V$			2	V
$V_{in(0)}$	Logical 0 input voltage required at one input terminal of each AND section to ensure output is in the off state	$V_{CC} = 4.5V$			0.8	V
$V_{on}$	On-state output voltage	$V_{CC} = 4.5V$ , $I_{on} = 5.85mA$	$V_{in} = 2V$ , $T_A = -55^\circ\text{C}$	$V_1 = 1V$	0.4	V
		$V_{CC} = 5.5V$ , $I_{on} = 7.85mA$	$V_{in} = 2V$ , $T_A = 125^\circ\text{C}$	$V_1 = 0.6V$	0.4	V
$I_{off}$	Off-state output current	$V_{CC} = 4.5V$ , $R = 575\Omega$	$V_{in} = 0.8V$ , $T_A = -55^\circ\text{C}$	$V_1 = 4.5V$	320	$\mu A$
$I_{on}$	On-state output current	$V_{CC} = 4.5V$ , $T_A = -55^\circ\text{C}$	$V_{in} = 2V$	$V_1 = 1V$	-470	$\mu A$

**SIGNETICS 3-2-2-3-INPUT AND-OR EXPANDER ■ S54H62**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = 5.5V,$	$V_{in} = 0.4V$			-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = 5.5V,$ $V_{CC} = 5.5V,$	$V_{in} = 2.4V$ $V_{in} = 5.5V$			50 1	$\mu A$ mA
$I_{CC(on)}$	On-state supply current	$V_{CC} = 5.5V,$ $V_1 = 0.85V$	$V_{in} = 4.5V,$		3.8	7	mA
$I_{CC(off)}$	Off-state supply current	$V_{CC} = 5.5V,$ $V_1 = 0.85V$	$V_{in} = 0,$		6	9	mA

**OUTPUT CAPACITANCE,  $V_{CC}$  and GND terminals open,  $T_A = 25^\circ C$**

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
Cx	Effective capacitance of output transistor $Q_1$	f = 1 MHz			1.3		pF

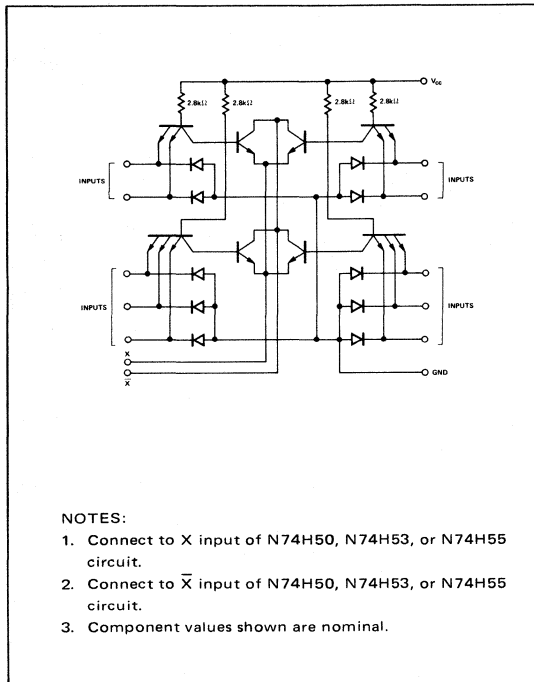
† All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

# Signetics 3-2-2-3-INPUT AND-OR EXPANDER (FOR USE WITH N74H50, N74H53, N74H55 CIRCUITS) **N74H62**

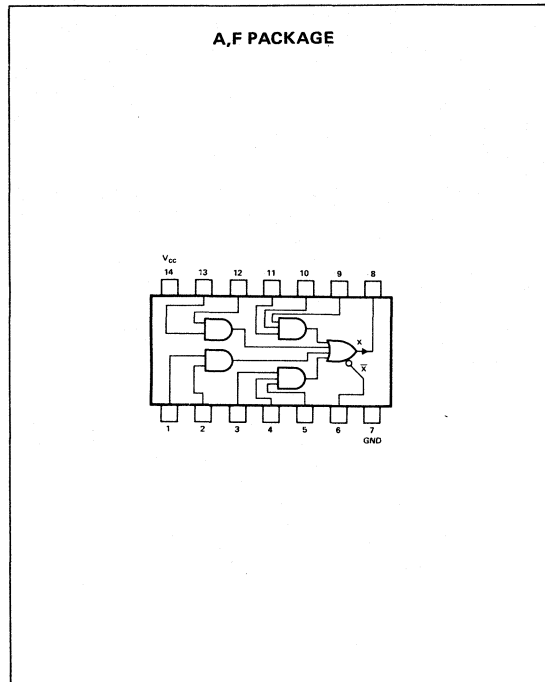
N74H62-A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

Supply Voltage $V_{CC}$	4.75V to 5.25V
Maximum number of expanders that may be fanned-in to one N74H50, N74H53, or N74H55 circuit	1

ELECTRICAL CHARACTERISTICS (unless otherwise noted  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ )

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT	
$V_{in(1)}$	Logical 1 input voltage required at all input terminals of one AND section to ensure output is in the on state	$V_{CC} = 4.75\text{V}$			2	V
$V_{in(0)}$	Logical 0 input voltage required at one input terminal of each AND section to ensure output is in the off state	$V_{CC} = 4.75\text{V}$			0.8	V
$V_{on}$	On-state output voltage	$V_{CC} = 4.75\text{V}, I_{on} = 6.3\text{mA}$	$V_{in} = 2\text{V}, T_A = 0^\circ\text{C}$	$V_1 = 1\text{V}$	0.4	V
		$V_{CC} = 5.25\text{V}, I_{on} = 7.4\text{mA}$	$V_{in} = 2\text{V}, T_A = 70^\circ\text{C}$	$V_1 = 0.6\text{V}$	0.4	V
$I_{off}$	Off-state output current	$V_{CC} = 4.75\text{V}, R = 575\Omega$	$V_{in} = 0.8\text{V}, T_A = 0^\circ\text{C}$	$V_1 = 4.5\text{V}$	570	$\mu\text{A}$
$I_{on}$	On-State output current	$V_{CC} = 4.75\text{V}, T_A = 0^\circ\text{C}$	$V_{in} = 2\text{V}$	$V_1 = 1\text{V}$	-600	$\mu\text{A}$



**SIGNETICS 3-2-2-3-INPUT AND-OR EXPANDER ■ N74H62**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{in(0)}$	Logical 0 level input current (each input)	$V_{CC} = 5.25V,$	$V_{in} = 0.4V$			-2	mA
$I_{in(1)}$	Logical 1 level input current (each input)	$V_{CC} = 5.25V,$	$V_{in} = 2.4V$			50	$\mu A$
		$V_{CC} = 5.25V,$	$V_{in} = 5.5V$			1	mA
$I_{CC(on)}$	On-state supply current	$V_{CC} = 5.25V,$	$V_{in} = 4.5V,$		3.8	7	mA
$I_{CC(off)}$	Off-state supply current	$V_1 = 0.85V$					
		$V_{CC} = 5.25V,$	$V_{in} = 0,$		6	9	mA
		$V_1 = 0.85V$					

$V_{CC}$  and GND terminals open,  $T_A = 25^\circ C$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
Cx	Effective capacitance of output transistor $Q_1$	f = 1 MHz			1.3		pF

† All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .

### DESCRIPTION

These J-K flip-flops are based on the master-slave principle. The AND-OR gate inputs for entry into the master section are controlled by the clock pulse. The clock pulse also regulates the circuitry which connects the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND-OR gate inputs to master
3. Disable AND-OR gate inputs
4. Transfer information from master to slave.

Logical state of J and K inputs must not be allowed to change when the clock pulse is in a high state.

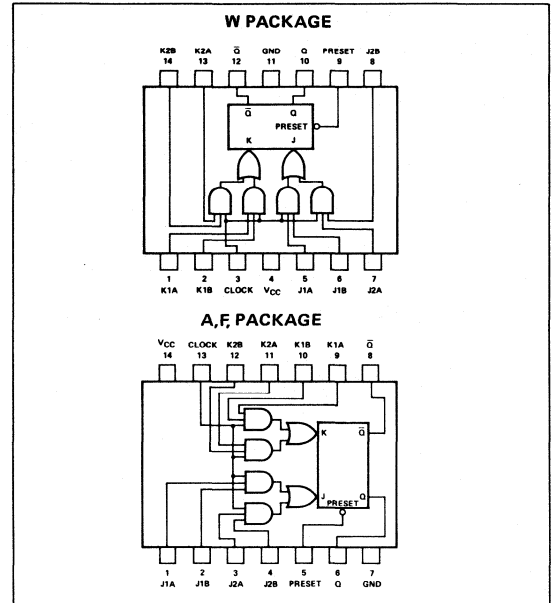
### TRUTH TABLE

$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

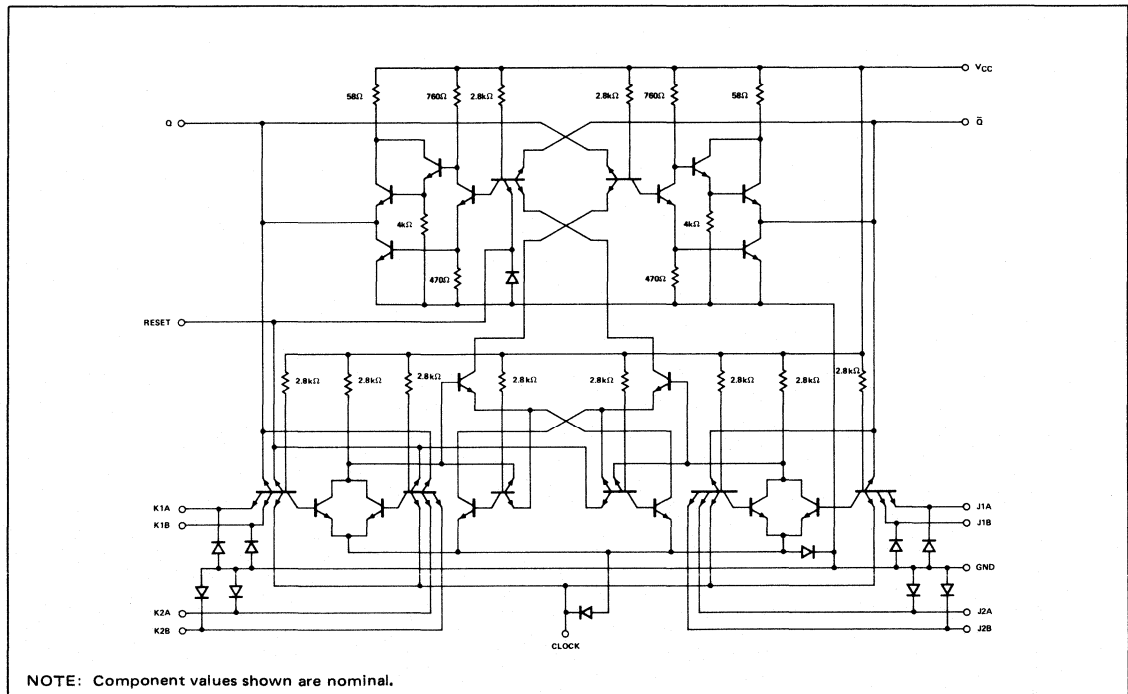
#### NOTES:

1.  $J = (J1A \bullet J1B) + (J2A \bullet J2B)$
2.  $K = (K1A \bullet K1B) + (K2A \bullet K2B)$
3.  $t_n$  = Bit time before clock pulse.
4.  $t_{n+1}$  = Bit time after clock pulse.

### PIN CONFIGURATIONS



### SCHEMATIC



# SIGNETICS J-K MASTER-SLAVE FLIP-FLOP ■ S54H71, N74H71

## RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H71 Circuits	4.5	5	5.5	V
N74H71 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H71 Circuits	-55	25	125	°C
N74H71 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	12			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	16			ns
Input Setup Time, $t_{\text{setup}}$ (See Above)	$\geq t_{p(\text{clock})}$			
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -500\mu\text{A}$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 20\text{mA}$			0.4	V
$I_{in(0)}$ Logical 0 level input current at J1A, J1B, J2A, J2B, K1A, K1B, K2A, or K2B	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-2	mA
$I_{in(0)}$ Logical 0 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-6	mA
$I_{in(0)}$ Logical 0 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$			-4	mA
$I_{in(1)}$ Logical 1 level input current at J1A, J1B, J2A, J2B, K1A, K1B, K2A, or K2B	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			50	$\mu\text{A}$
$I_{in(1)}$ Logical 1 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			150	$\mu\text{A}$
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			100	$\mu\text{A}$
$I_{OS}$ Short-circuit output current **	$V_{CC} = \text{MAX}, V_{in} = 0$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$		19	30	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum clock frequency	$C_L = 25\text{ pF}, R_L = 280\Omega$	25	30		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from preset to output	$C_L = 25\text{ pF}, R_L = 280\Omega$		6	13	ns
$t_{pd0}$ Propagation delay time to logical 0 level from preset to output	$C_L = 25\text{ pF}, R_L = 280\Omega$		12	24	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{ pF}, R_L = 280\Omega$	6	14	21	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{ pF}, R_L = 280\Omega$	10	22	27	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

S54H72--A,F,W • N74H72--A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These J-K flip-flops are based on the master-slave principle. The AND gate inputs for entry into the master section are controlled by the clock pulse. The clock pulse also regulates the circuitry which connects the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND gate inputs to master
3. Disable AND gate inputs
4. Transfer information from master to slave.

Logical state of J and K inputs must not be allowed to change when the clock pulse is in a high state

### TRUTH TABLE

#### LOGIC

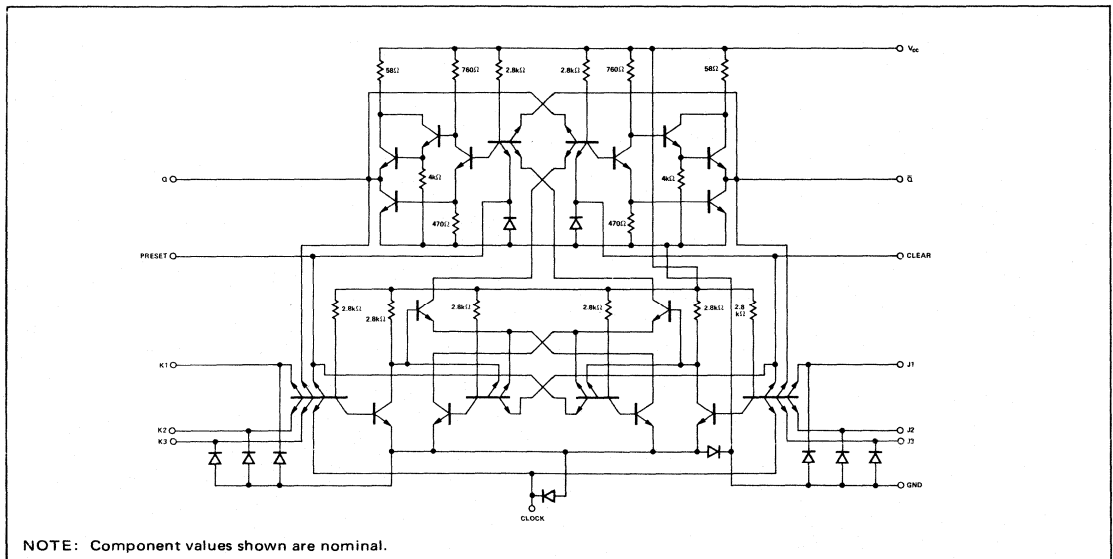
(Each Flip-Flop)			
$t_n$		$t_{n+1}$	
J	K	Q	
0	0	$Q_n$	
0	1	0	
1	0	1	
1	1	$\bar{Q}_n$	

#### NOTES:

1.  $J = J_1 \cdot J_2 \cdot J_3$
2.  $K = K_1 \cdot K_2 \cdot K_3$
3.  $t_n$  = bit time before clock pulse
4.  $t_{n+1}$  = bit time after clock pulse.

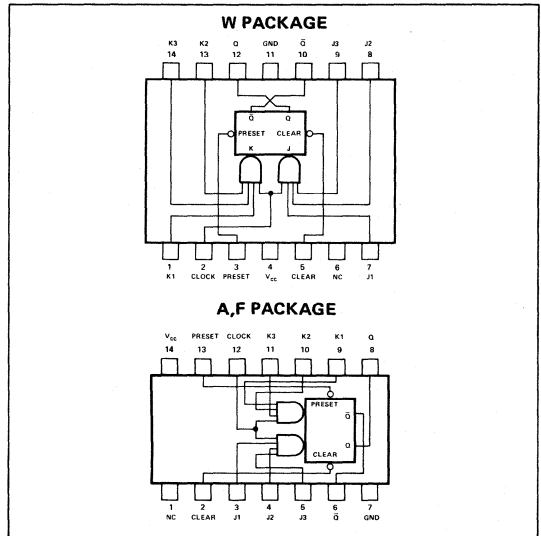
Low input to preset sets Q to logical 1  
 Low input to clear sets Q to logical 0  
 Preset and clear are independent of clock

### SCHEMATIC DIAGRAM

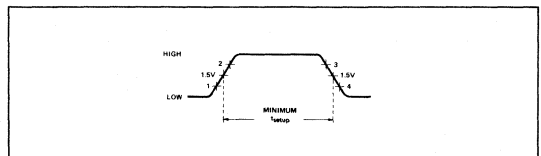


NOTE: Component values shown are nominal.

### PIN CONFIGURATIONS



### CLOCK WAVEFORM



# SIGNETICS J-K MASTER-SLAVE FLIP-FLOP ■ S54H72, N74H72

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H72 Circuits	4.5	5	5.5	V
N74H72 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H72 Circuits	-55	25	125	°C
N74H72 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	12			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	16			ns
Width of Clear Pulse, $t_{p(\text{clear})}$	16			ns
Input Setup Time, $t_{\text{setup}}$ (See above)	$\geq t_{p(\text{clock})}$			
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$ ,			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -500\mu\text{A}$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 20\text{mA}$			0.4	V
$I_{in(0)}$ Logical 0 level input current at J1, J2, J3, K1, K2, K3, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-2	mA
$I_{in(0)}$ Logical 0 level input current at preset or clear	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-4	mA
$I_{in(1)}$ Logical 1 level input current at J1, J2, J3, K1, K2, or K3	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at preset or clear	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			100 1	$\mu\text{A}$ mA
$I_{OS}$ Short circuit output current**	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ ,		16	25	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum clock frequency	$C_L = 25\text{pF}$ , $R_L = 280\Omega$	25	30		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from clear or preset to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		6	13	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear or preset to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		12	24	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		16	21	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		22	27	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

### DESCRIPTION

These J-K flip-flops are based on the master-slave principle. The AND gate inputs for entry into the master section are controlled by the clock pulse. The clock pulse also regulates the circuitry which connects the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from AND gate inputs to master
3. Disable AND gate inputs
4. Transfer information from master to slave.

Logical state of J and K inputs must not be allowed to change when the clock pulse is in a high state.

### TRUTH TABLE

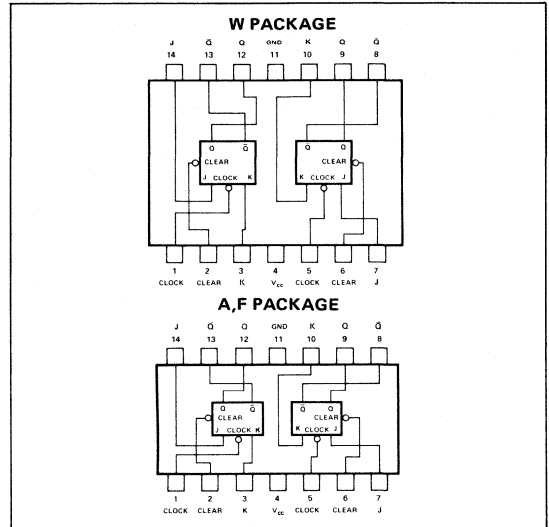
#### LOGIC

(Each Flip-Flop)		
$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

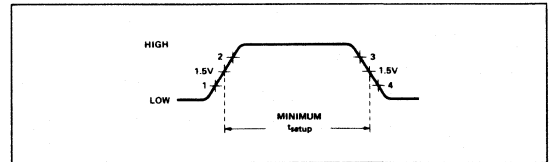
#### NOTES:

1.  $t_n$  = bit time before clock pulse
2.  $t_{n+1}$  = bit time after clock pulse

### PIN CONFIGURATIONS



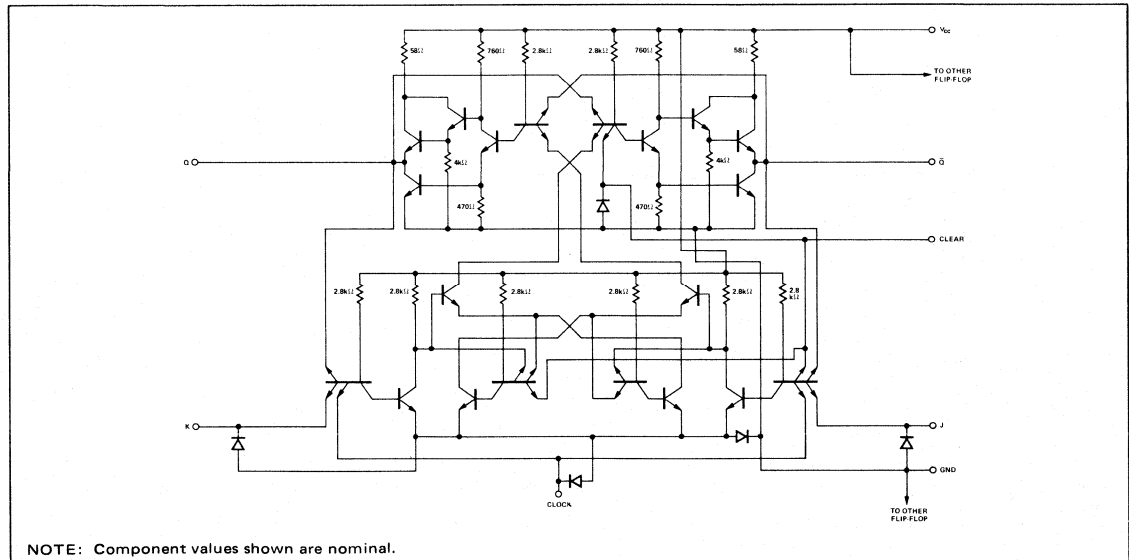
### CLOCK WAVEFORM



### POSITIVE LOGIC

Low input to clear sets Q to logical 0  
Clear is independent of clock

### SCHEMATIC (each flip-flop)



NOTE: Component values shown are nominal.

## SIGNETICS DUAL J-K MASTER-SLAVE FLIP-FLOP ■ S54H73, N74H73

### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H73 Circuits	4.5	5	5.5	V
N74H73 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H73 Circuits	-55	25	125	°C
N74H73 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	12			ns
Width of Clear Pulse, $t_{p(\text{clear})}$	16			ns
Input Setup Time, $t_{\text{setup}}$ (See above)	$\geq t_{p(\text{clock})}$			
Input Hold Time, $t_{\text{hold}}$	0			

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS**	MIN	TYP†	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2		V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$		0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -500\mu\text{A}$	2.4		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 20\text{mA}$		0.4	V
$I_{in(0)}$	Logical 0 level input current at J, K, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	mA
$I_{in(0)}$	Logical 0 level input current at clear	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-4	mA
$I_{in(1)}$	Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$		50 1	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$		50 1	$\mu\text{A}$ mA
$I_{in(1)}$	Logical 1 level input current at clear	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$		100 1	$\mu\text{A}$ mA
$I_{OS}$	Short circuit output current**	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	-40	-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$	32	50	mA

### SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , $N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$	Maximum clock frequency	$C_L = 25\text{pF}$ , $R_L = 280\Omega$	25	30	MHz
$t_{pd1}$	Propagation delay time to logical 1 level from clear to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		6	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clear to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		12	ns
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		16	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		22	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$

S54H74-A,F,W • N74H74-A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These monolithic, high-speed, dual, edge-triggered flip-flops utilize TTL circuitry to perform D-type flip-flop logic. Each flip-flop has individual clear and preset inputs, and also complementary Q and  $\bar{Q}$  outputs.

Information at input D is transferred to the Q output on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level of the clock pulse and is not directly related to the transition time of the positive-going pulse. When the clock input is at either the high or low level, the D-input signal has no effect.

These circuits are fully compatible for use with most TTL or DTL circuits. Input clamping diodes are provided to minimize transmission line effects and thereby simplify systems design. A full fan-out to 10 normalized Series 54H/74H loads is available from each of the outputs in the low-level condition. In the high-level state, a fan-out of 20 is available to facilitate tying unused inputs to used inputs. Maximum clock frequency is 35 megahertz, with a typical power dissipation of 75 milliwatts per flip-flop.

### TRUTH TABLE

#### LOGIC

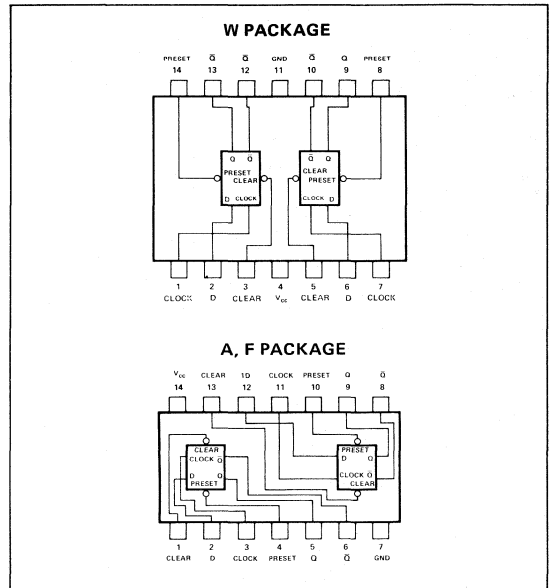
(Each Flip-Flop)		
$t_n$		$t_{n+1}$
Input D	Output Q	Output $\bar{Q}$
L	L	H
H	H	L

H = High Level, L = Low Level

#### NOTES:

- $t_n$  = bit time before clock pulse
- $t_{n+1}$  = bit time after clock pulse

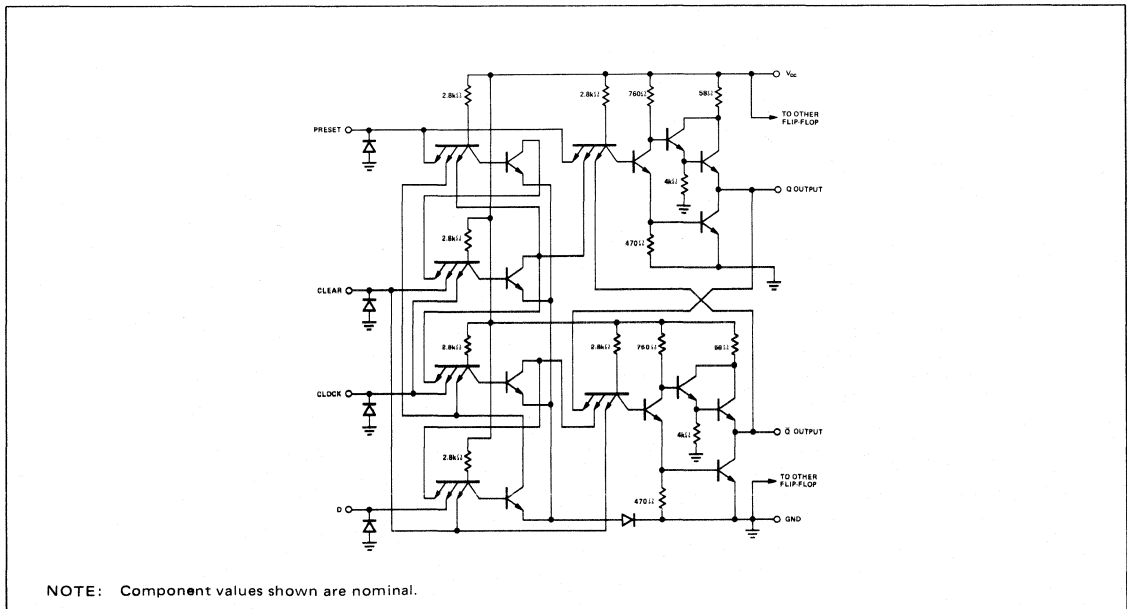
### PIN CONFIGURATIONS



### ASYNCHRONOUS INPUTS

Low input to preset sets Q to high level  
 Low input to clear sets Q to low level  
 Preset and clear are independent of clock

### SCHEMATIC (each flip-flop)





**SIGNETICS DUAL D-TYPE EDGE-TRIGGERED FLIP-FLOP ■ S54H74, N74H74**

**RECOMMENDED OPERATING CONDITIONS**

PARAMETER	S54H74			N74H74			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N							
Low Logic Level			10			10	
High Logic Level			20			20	
Clock Frequency, $f_{clock}$	0		35†	0		35	MHz
Width of Clock Pulse, $t_w(\text{clock})$	15†			15†			ns
Width of Preset Pulse, $t_w(\text{preset})$	25†			25†			ns
Width of Clear Pulse, $t_w(\text{clear})$	25†			25†			ns
Input Setup Time, $t_{setup}$ (See Note 3):							
High-level data	10†			10†			ns
Low-level data	15†			15†			ns
Input Hold Time, $t_{hold}$ (See Note 4)	0			0			ns
Operating Free-Air Temperature Range, $T_A$	-55	25	125	0	25	70	°C

**NOTES:**

- Setup time is the interval immediately preceding the positive-going edge of the clock pulse during which interval the data to be recognized must be maintained at the input to ensure its recognition.
- Hold time is the interval immediately following the positive-going edge of the clock pulse during which interval the data to be recognized must be maintained at the input to ensure its continued recognition.

† These conditions are recommended for use at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_{OH} = -1\text{mA}$	3.5		V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, I_{OL} = 20\text{mA}$	0.22	0.4	V
$I_{IH}$	High-level input current into D	$V_{CC} = \text{MAX}, V_I = 2.4V$		50	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_I = 5.5V$		1	mA
$I_{IH}$	High-level input current into preset or clock	$V_{CC} = \text{MAX}, V_I = 2.4V$		100	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_I = 5.5V$		1	mA
$I_{IH}$	High-level input current into clear	$V_{CC} = \text{MAX}, V_I = 2.4V$		150	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_I = 5.5V$		1	mA
$I_{IL}$	Low-level input current into preset or D	$V_{CC} = \text{MAX}, V_I = 0.4V$		-2	mA
$I_{IL}$	Low-level input current into clear or clock	$V_{CC} = \text{MAX}, V_I = 0.4V$		-4	mA
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX},$		-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX},$		42	mA
		S54H74	30		
		N74H74	30	50	

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum clock frequency	35	43		MHz
$t_{PLH}$	Propagation delay time, low-to-high-level output, from clear or preset inputs			20	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output, from clear or preset inputs	$C_L = 25\text{pF},$	$R_L = 280\Omega$	30	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output from clock input	4	8.5	15	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output, from clock input	7	13	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time, and duration of short circuit test should not exceed 1 second.

S54H76-B • N74H76-B

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These dual J-K flip-flops are based on the master-slave principle. Inputs to the master section are controlled by the clock pulse. The clock pulse also regulates the circuitry which connects the master and slave sections. The sequence of operation is as follows:

1. Isolate slave from master
2. Enter information from J and K inputs to master
3. Disable J and K inputs
4. Transfer information from master to slave.

Logical state of J and K inputs must not be allowed to change when the clock pulse is in a high state.

### TRUTH TABLE

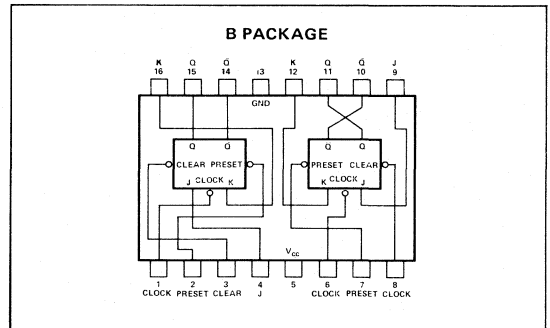
#### LOGIC

		$t_n$	$t_{n+1}$
J	K	Q	$\bar{Q}$
0	0	Q <sub>n</sub>	$\bar{Q}_n$
0	1	0	1
1	0	1	0
1	1	1	$\bar{Q}_n$

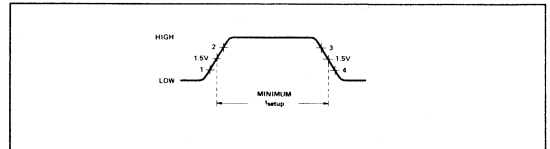
#### NOTES:

1.  $t_n$  = bit time before clock pulse
2.  $t_{n+1}$  = bit time after clock pulse

### PIN CONFIGURATIONS



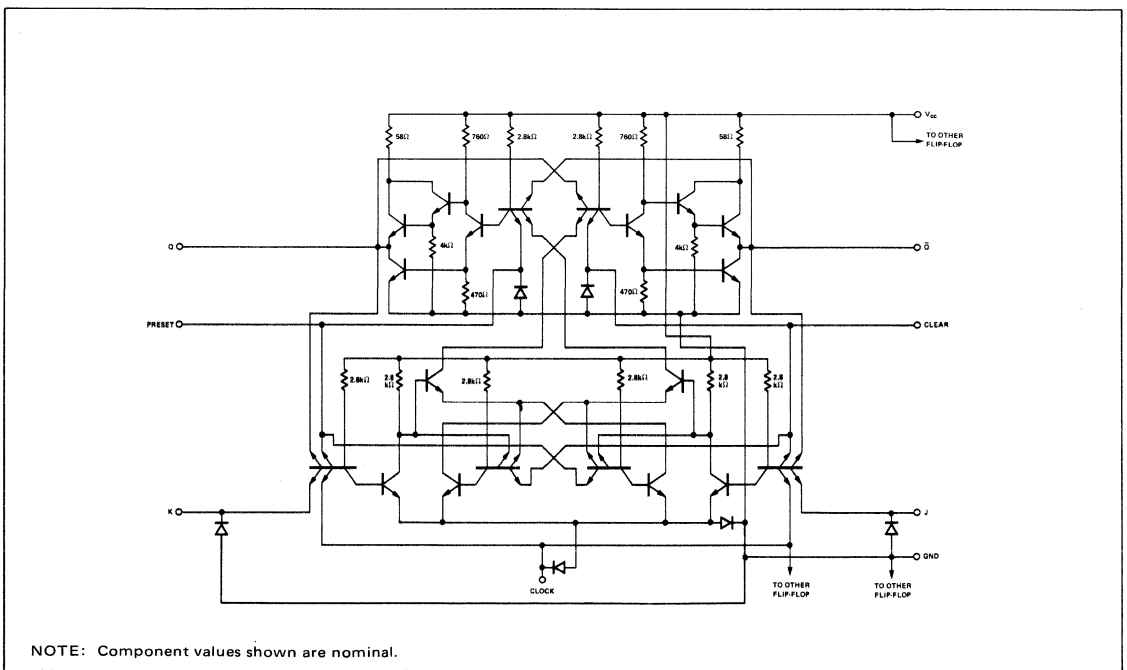
### CLOCK WAVEFORM



### POSITIVE LOGIC

Low input to preset sets Q to logical 1  
Low input to clear sets Q to logical 0  
Clear and preset are independent of clock

### SCHEMATIC (each flip-flop)



NOTE: Component values shown are nominal.

# SIGNETICS DUAL J-K MASTER-SLAVE FLIP-FLOP ■ S54H76, N74H76

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H76 Circuits	4.5	5	5.5	V
N74H76 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H76 Circuits	-55	25	125	°C
N74H76 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	12			ns
Width of Preset Pulse, $t_p(\text{preset})$	16			ns
Width of Clear Pulse, $t_p(\text{clear})$	$\geq t_p(\text{clock})$			
Input Setup Time, $t_{\text{setup}}$ (See above)				
Input Hold Time, $t_{\text{hold}}$	0			

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP <sup>†</sup>	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal	$V_{CC} = \text{MIN}$	2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal	$V_{CC} = \text{MIN}$			0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -500\mu\text{A}$	2.4			V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 20\text{mA}$			0.4	V
$I_{in(0)}$ Logical 0 level input current at J, K, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-2	mA
$I_{in(0)}$ Logical 0 level input current at clear or preset	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$			-4	mA
$I_{in(1)}$ Logical 1 level input current at J, K, or clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at clear or preset	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			100 1	$\mu\text{A}$ mA
$I_{OS}$ Short circuit output current**	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , $V_{in} = 4.5\text{V}$		32	50	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum clock frequency	$C_L = 25\text{pF}$ , $R_L = 280\Omega$	25	30		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from clear or preset to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		6	13	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear or preset to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		12	24	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		16	21	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{pF}$ , $R_L = 280\Omega$		22	27	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

† All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

\*\* Not more than one output should be shorted at a time.

### DESCRIPTION

These monolithic J-K flip-flops are negative-edge-triggered. The AND-OR gate inputs are inhibited while the clock input is low; when the clock goes high, the inputs are enabled and data will be accepted. Logical state of J and K inputs may be allowed to change when the clock pulse is in a high state and bistable-will perform according to the truth table as long as minimum setup times are observed. Input data are transferred to the outputs on the negative edge of the clock pulse.

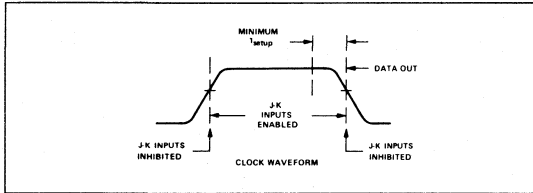
### TRUTH TABLE

J	K	Q <sub>n</sub>	Q <sub>n+1</sub>
0	0	0	0
0	1	0	0
1	0	1	1
1	1	1	0

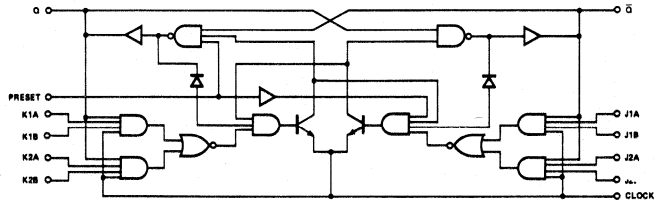
#### NOTES:

1.  $J = (J1A \bullet J1B) + (J2A \bullet J2B)$
2.  $K = (K1A \bullet K1B) + (K2A \bullet K2B)$
3.  $t_n$  = Bit time before clock pulse
4.  $t_{n+1}$  = Bit time after clock pulse

### CLOCK WAVEFORM

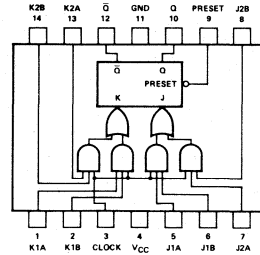


### LOGIC DIAGRAM

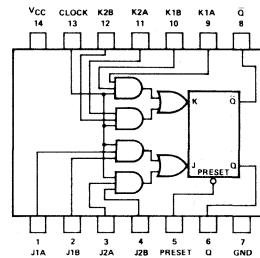


### PIN CONFIGURATIONS

#### W PACKAGE



#### A,F PACKAGE



# SIGNETICS J-K EDGE-TRIGGERED FLIP-FLOP ■ S54H101, N74H101

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H101 Circuits	4.5	5	5.5	V
N74H101 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H101 Circuits	-55	25	125	°C
N74H101 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	10			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	16			ns
Input Setup Time, $t_{\text{setup}}$ (See Above): Logical 1	10			ns
Logical 0	13			ns
Input Hold Time, $t_{\text{hold}}$	0			ns
Clock Pulse Transition Time, $t_0$			150	ns

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -500\mu\text{A}$	2.4	3.2		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 20 \text{ mA}$		0.25	0.4	V
$I_{in(0)}$ Logical 0 level input current at J1A, J1B, J2A, J2B, K1A, K1B, K2A, K2B, or preset	$V_{CC} = \text{MAX}, V_{in} = 0.4 \text{ V}$		-1	-2	mA
$I_{in(0)}$ Logical 0 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 0.4 \text{ V}$		-3	-4.8	mA
$I_{in(1)}$ Logical 1 level input current at J or K	$V_{CC} = \text{MAX}, V_{in} = 2.4 \text{ V}$			50	$\mu\text{A}$
$I_{in(1)}$ Logical 1 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 5.5 \text{ V}$			1	mA
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 2.4 \text{ V}$			100	$\mu\text{A}$
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 5.5 \text{ V}$			1	mA
$I_{OS}$ Short-circuit output current**	$V_{CC} = \text{MAX}, V_{in} = 5.5 \text{ V}$	0		-1	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}, V_{in} = 0$	-40		-100	mA
			20	38	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum input clock frequency	$C_L = 25 \text{ pF}, R_L = 280 \Omega$	40	50		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from preset to output	$C_L = 25 \text{ pF}, R_L = 280 \Omega$		8	12	ns
$t_{pd0}$ Propagation delay time to logical 0 level from preset to output (clock low)	$C_L = 25 \text{ pF}, R_L = 280 \Omega$		23	35	ns
$t_{pd0}$ Propagation delay time to logical 0 level from preset to output (clock high)	$C_L = 25 \text{ pF}, R_L = 280 \Omega$		15	20	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25 \text{ pF}, R_L = 280 \Omega$	5	10	15	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25 \text{ pF}, R_L = 280 \Omega$	8	16	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

S54H102--A,F,W • N74H102--A,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These monolithic J-K flip-flops are negative edge-triggered. They feature gated J-K inputs and an asynchronous clear input. The AND gate inputs are inhibited while the clock input is low; when the clock goes high, the inputs are enabled and data will be accepted. Logical state of J and K inputs may be allowed to change when the clock pulse is in a high state and bistable-will perform according to the truth table as long as minimum setup times are observed. Input data are transferred to the outputs on the negative edge of the clock pulse.

### TRUTH TABLE

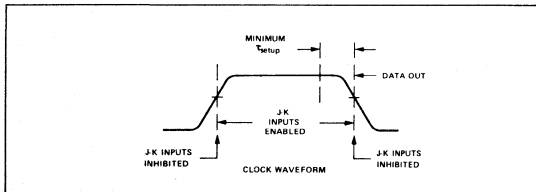
#### LOGIC

$t_n$		$t_{n+1}$	
J	K	Q	$\bar{Q}$
0	0	$Q_n$	$\bar{Q}_n$
0	1	0	1
1	0	1	0
1	1	$\bar{Q}_n$	$Q_n$

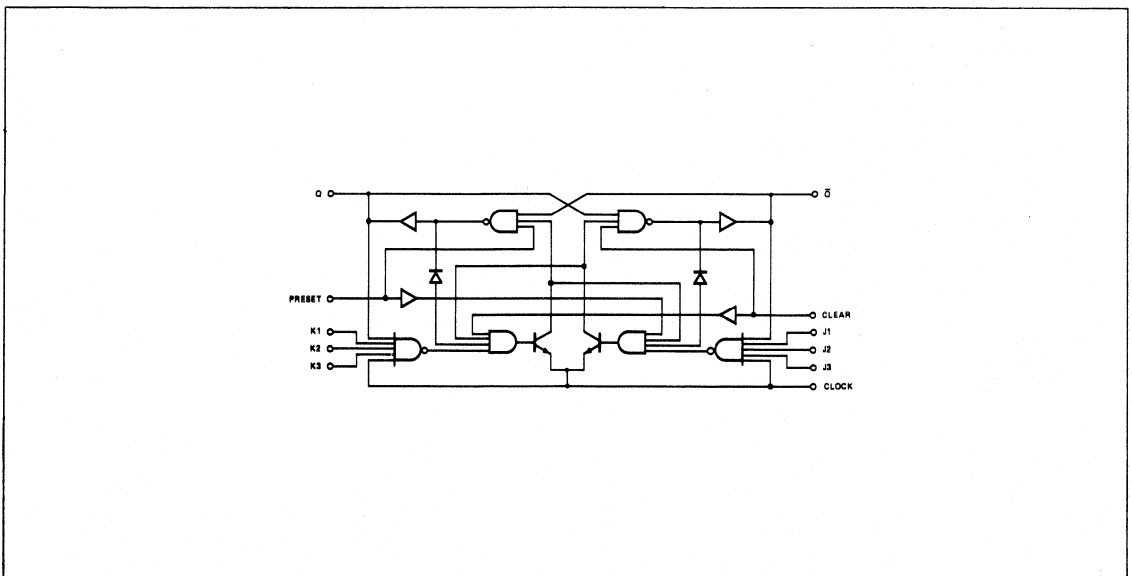
#### NOTES:

1.  $J = J1 \bullet J2 \bullet J3$
2.  $K = K1 \bullet K2 \bullet K3$
3.  $t_n$  = Bit time before clock pulse.
4.  $t_{n+1}$  = Bit time after clock pulse.
5. NC—No Internal Connection.

### CLOCK WAVEFORM

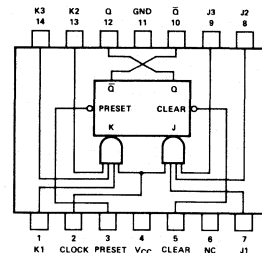


### LOGIC DIAGRAM

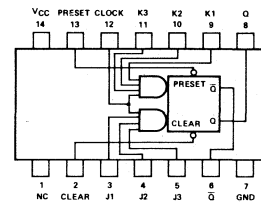


### PIN CONFIGURATIONS

#### W PACKAGE



#### A,F PACKAGE



# SIGNETICS J-K EDGE-TRIGGERED FLIP-FLOPS WITH AND INPUTS ■ S54H102, N74H102

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H102 Circuits	4.5	5	5.5	V
N74H102 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H102 Circuits	-55	25	125	°C
N74H102 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_{p(\text{clock})}$	10			ns
Width of Preset Pulse, $t_{p(\text{preset})}$	15			ns
Width of Clear Pulse, $t_{p(\text{clear})}$	15			ns
Input Setup Time, $t_{\text{setup}}$ (See Above): Logical 1	10			ns
Logical 0	13			ns
Input Hold Time, $t_{\text{hold}}$	0			ns
Clock Pulse Transition Time, $t_0$			150	ns

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -500\mu\text{A}$	2.4	3.2		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 20\text{mA}$		0.25	0.4	V
$I_{in(0)}$ Logical 0 level input current at J1, J2, J3, K1, K2, K3, preset, or clear	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$		-1	-2	mA
$I_{in(0)}$ Logical 0 level input current clock	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$		-3	-4.8	mA
$I_{in(1)}$ Logical 1 level input current at J1, J2, J3, K1, K2, or K3	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			50	$\mu\text{A}$
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$	0		-1	mA
	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$ Logical 1 level input current at preset or clear	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$			100	$\mu\text{A}$
	$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			1	mA
$I_{OS}$ Short-circuit output current**	$V_{CC} = \text{MAX}, V_{in} = 0$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$		20	38	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum input clock frequency	$C_L = 25\text{pF}, R_L = 280\Omega$	40	50		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from preset to output	$C_L = 25\text{pF}, R_L = 280\Omega$		8	12	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear or preset to output (clock low)	$C_L = 25\text{pF}, R_L = 280\Omega$		23	35	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear or preset to output (clock high)	$C_L = 25\text{pF}, R_L = 280\Omega$		15	20	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{pF}, R_L = 280\Omega$	5	10	15	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{pF}, R_L = 280\Omega$	8	16	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

### DESCRIPTION

These dual monolithic J-K flip-flops are negative-edge-triggered. They feature individual J, K, clock, and asynchronous clear inputs to each flip-flop. When the clock goes high, the inputs are enabled and data will be accepted. Logical state of J and K inputs may be allowed to change when the clock pulse is in a high state and bistable-will perform according to the truth table as long as minimum setup times are observed. Input data are transferred to the outputs on the negative edge of the clock pulse.

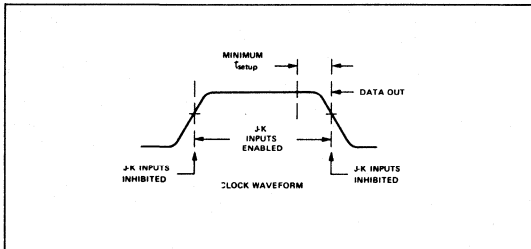
### TRUTH TABLE

J	$t_n$	K	$t_{n+1}$	Q
0	0	0	$Q_n$	0
0	1	0	$Q_n$	1
1	0	1	$Q_n$	0
1	1	1	$Q_n$	$\overline{Q_n}$

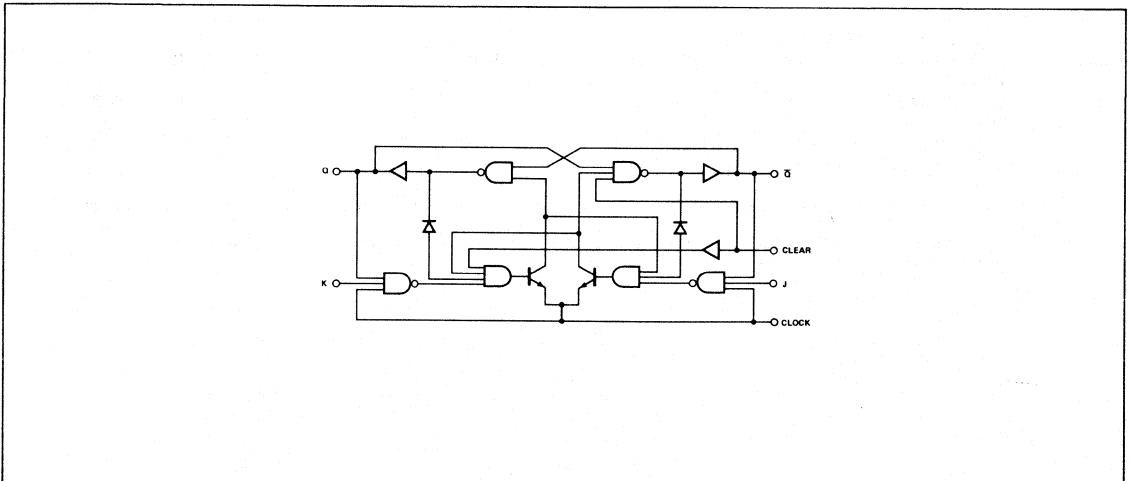
#### NOTES:

- $t_n$  = Bit time before clock pulse
- $t_{n+1}$  = Bit time after clock pulse

### CLOCK WAVEFORM

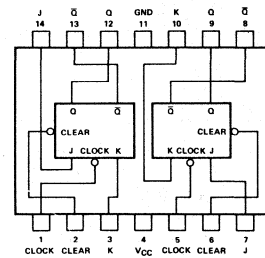


### LOGIC DIAGRAM (each flip-flop)

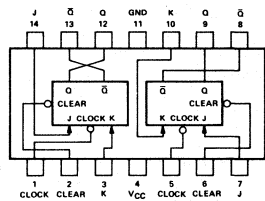


### PIN CONFIGURATIONS

#### W PACKAGE



#### A,F PACKAGE





**SIGNETICS DUAL J-K EDGE-TRIGGERED FLIP-FLOP ■ S54H103, N74H103**

**RECOMMENDED OPERATING CONDITIONS**

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H103 Circuits N74H103 Circuits	4.5 4.75	5 5	5.5 5.25	V V
Operating Free-Air Temperature Range, $T_A$ : S54H103 Circuits N74H103 Circuits	-55 0	25 25	125 70	°C °C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	10			ns
Width of Clear Pulse, $t_p(\text{clear})$	16			ns
Input Setup Time, $t_{\text{setup}}$ : Logical 1	10			ns
Logical 0	13			ns
Input Hold Time, $t_{\text{hold}}$	0			ns
Clock Pulse Transition Time, $t_0$			150	ns

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS *	MIN	TYP <sup>†</sup>	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -500\mu\text{A}$	2.4	3.2		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 20\text{mA}$		0.25	0.4	V
$I_{in(0)}$ Logical 0 level input current at J, K, or clear	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$		-1	-2	mA
$I_{in(0)}$ Logical 0 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 0.4\text{V}$		-3	-4.8	mA
$I_{in(1)}$ Logical 1 level input current at J or K	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			50 1	$\mu\text{A}$ mA
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$	0		-1 1	mA mA
$I_{in(1)}$ Logical 1 level input current at clear	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$ $V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$			100 1	$\mu\text{A}$ mA
$I_{OS}$ Short-circuit output current **	$V_{CC} = \text{MAX}, V_{in} = 0$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$		40	76	mA

**SWITCHING CHARACTERISTICS,  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum input clock frequency	$C_L = 25\text{pF}, R_L = 280\Omega$	40	50		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from clear to output	$C_L = 25\text{pF}, R_L = 280\Omega$		8	12	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear to output (clock low)	$C_L = 25\text{pF}, R_L = 280\Omega$		23	35	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clear to output (clock high)	$C_L = 25\text{pF}, R_L = 280\Omega$		15	20	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{pF}, R_L = 280\Omega$	5	10	15	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{pF}, R_L = 280\Omega$	8	16	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed one second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

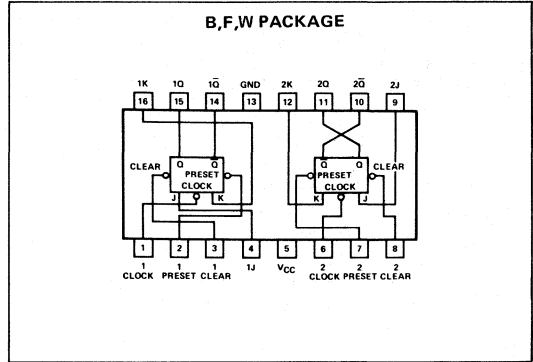
S54H106-B,F,W • N54H106-B,F

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These dual monolithic J-K flip-flops are negative edge-triggered. They feature individual J, K, clock, and asynchronous preset and clear inputs to each flip-flop. When the clock goes high, the inputs are enabled and data will be accepted. Logical state of J and K inputs may be allowed to change when the clock pulse is in a high state and bistable will perform according to the truth table as long as minimum set-up times are observed. Input data is transferred to the outputs on the negative edge of the clock pulse.

### PIN CONFIGURATION

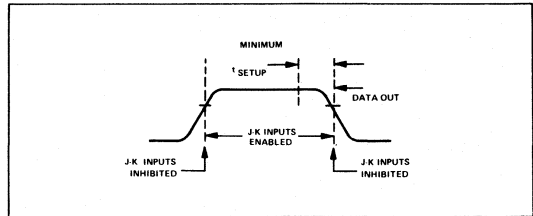


$t_n$		$t_{n+1}$
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

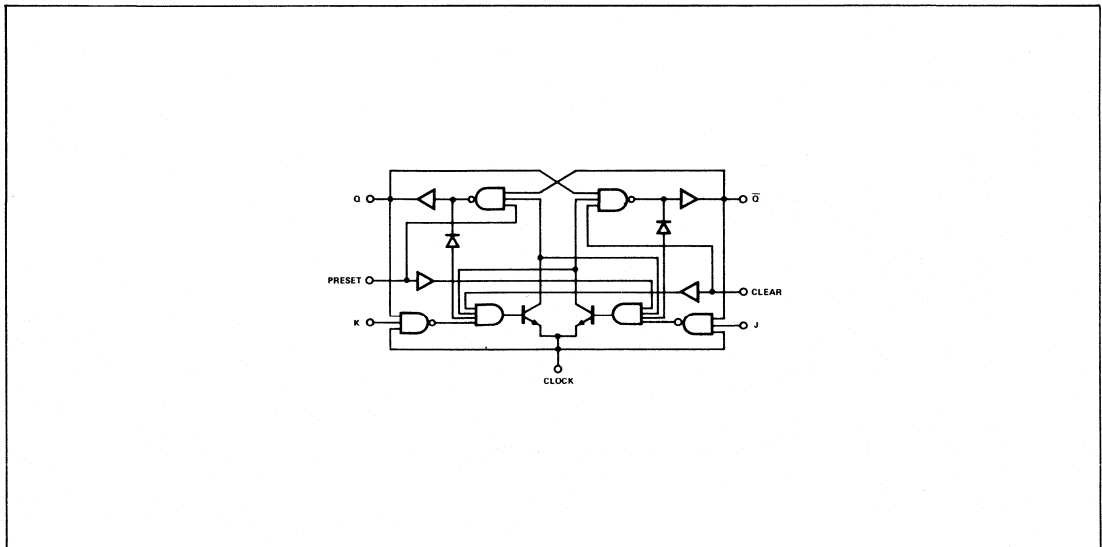
#### NOTES:

1.  $t_n$  = Bit time before clock pulse.
2.  $t_{n+1}$  = Bit time after clock pulse.

### CLOCK WAVEFORM

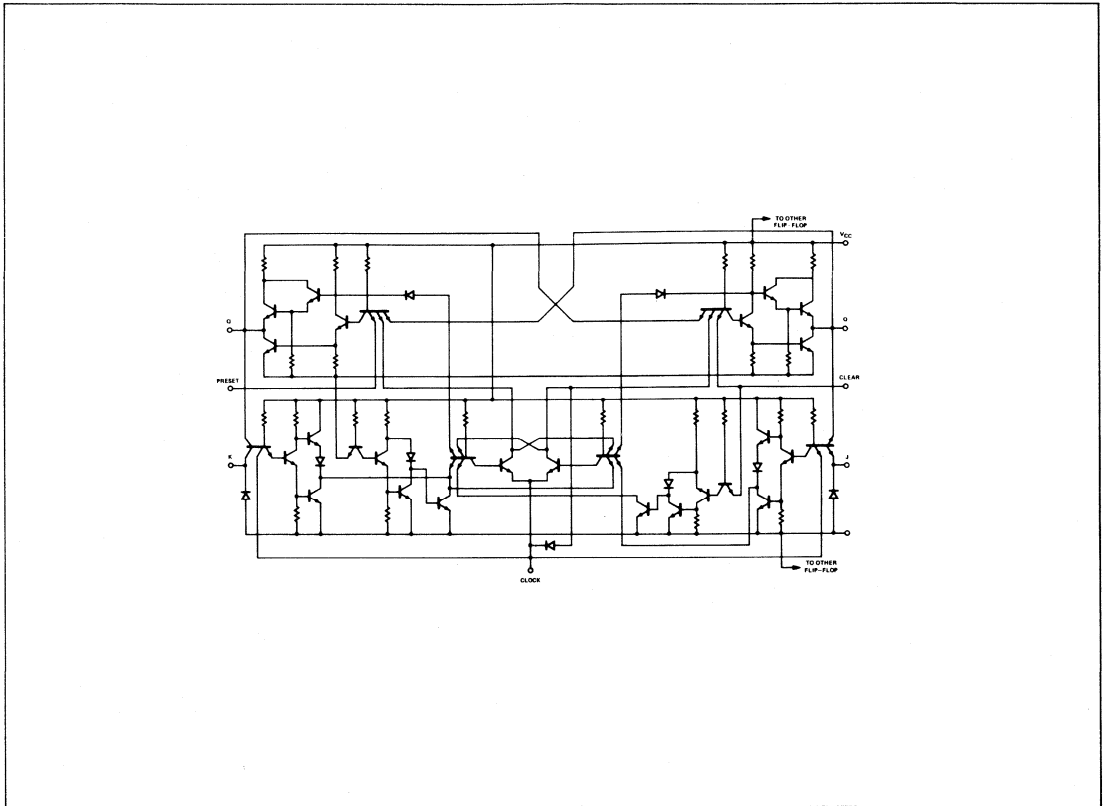


### BLOCK DIAGRAM (each flip-flop)



SIGNETICS DUAL J-K EDGE-TRIGGERED FLIP-FLOP ■ S54H106, N74H106

SCHEMATIC DIAGRAM (each flip-flop)



RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H106 Circuits	4.5	5	5.5	V
N74H106 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H106 Circuits	-55	25	125	$^{\circ}C$
N74H106 Circuits	0	25	70	$^{\circ}C$
Normalized Fan-Out From Each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	10			ns
Width of Preset Pulse, $t_p(\text{preset})$	16			ns
Width of Clear Pulse, $t_p(\text{clear})$	16			ns
Input Setup Time, $t_{\text{setup}}$ (See Above): Logical 1	10			ns
Logical 0	13			ns
Input Hold Time, $t_{\text{hold}}$	0			ns
Clock Pulse Transition Time, $t_0$			150	ns

## SIGNETICS DUAL J-K EDGE-TRIGGERED FLIP-FLOP ■ S54H106, N74H106

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{load} = 500 \mu\text{A}$	2.4	3.2		V
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{sink} = 20 \text{ mA}$		0.25	0.4	V
$I_{in(0)}$	Logical 0 level input current at J, K, preset, or clear	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4 \text{ V}$		-1	-2	mA
$I_{in(0)}$	Logical 0 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4 \text{ V}$		-3	-4.8	mA
$I_{in(1)}$	Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4 \text{ V}$			50	$\mu\text{A}$
$I_{in(1)}$	Logical 1 level input current at present or clear	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5 \text{ V}$			1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4 \text{ V}$			100	$\mu\text{A}$
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5 \text{ V}$			1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4 \text{ V}$	0		-1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5 \text{ V}$			1	mA
$I_{OS}$	Short-circuit output current‡	$V_{CC} = \text{MAX}$ , $V_{in} = 0$	-40		-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$		40	76	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

‡Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

§All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

SWITCHING CHARACTERISTICS,  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^\circ\text{C}$ ,  $N = 10$

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{clock}$	Maximum input clock frequency	$C_L = 25 \text{ pF}$ , $R_L = 280 \Omega$	40	50		MHz
$t_{pd1}$	Propagation delay time to logical 1 level from preset or clear to output	$C_L = 25 \text{ pF}$ , $R_L = 280 \Omega$		8	12	ns
$t_{pd0}$	Propagation delay time to logical 0 level from preset or clear to output (clock low)	$C_L = 25 \text{ pF}$ , $R_L = 280 \Omega$		23	35	ns
$t_{pd0}$	Propagation delay time to logical 0 level from preset or clear to output (clock high)	$C_L = 25 \text{ pF}$ , $R_L = 280 \Omega$		15	20	ns
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output	$C_L = 25 \text{ pF}$ , $R_L = 280 \Omega$	5	10	15	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output	$C_L = 25 \text{ pF}$ , $R_L = 280 \Omega$	8	16	20	ns

#### DESCRIPTION

These dual monolithic J-K flip-flops are negative-edge-triggered. They feature individual J, K, and asynchronous preset inputs to each flip-flop as well as common clock and asynchronous clear inputs. When the clock goes high, the inputs are enabled and data is accepted. Logical state of J and K inputs may be allowed to change when the clock pulse is in a high state and bistable performs according to the truth table as long as minimum set-up times are observed. Data input is transferred to the outputs on the negative edge of the clock pulse.

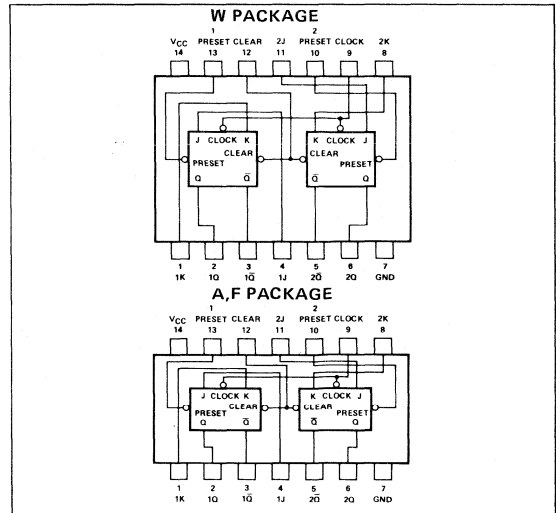
#### TRUTH TABLE

LOGIC		
$t_n$	$t_{n+1}$	
J	K	Q
0	0	$Q_n$
0	1	0
1	0	1
1	1	$\bar{Q}_n$

NOTES:

- $t_n$  = bit time before clock pulse
- $t_{n+1}$  = bit time after clock pulse

#### PIN CONFIGURATIONS



#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H108 Circuits	4.5	5	5.5	V
N74H108 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H108 Circuits	-55	25	125	$^{\circ}$ C
N74H108 Circuits	0	25	70	$^{\circ}$ C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	10			ns
Width of Preset Pulse, $t_p(\text{preset})$	15			ns
Width of Clear Pulse, $t_p(\text{clear})$	16			ns
Input Setup Time, $t_{\text{setup}}$ Logical 1	10			ns
Logical 0	13			ns
Input Hold Time, $t_{\text{hold}}$	0			ns
Clock Pulse Transition Time, $t_0$			150	ns

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP <sup>†</sup>	MAX	UNIT	
$V_{in(1)}$	Input voltage required to ensure logical 1 at any input terminal		2		V	
$V_{in(0)}$	Input voltage required to ensure logical 0 at any input terminal			0.8	V	
$V_{out(1)}$	Logical 1 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{load}} = -500\mu\text{A}$	2.4	3.2	V	
$V_{out(0)}$	Logical 0 output voltage	$V_{CC} = \text{MIN}$ , $I_{\text{sink}} = 20\text{mA}$		0.25	V	
$I_{in(0)}$	Logical 0 level input current at J, K, or preset	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-1	-2	mA
$I_{in(0)}$	Logical 0 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-6	-9.6	mA
$I_{in(0)}$	Logical 0 level input current at clear	$V_{CC} = \text{MAX}$ , $V_{in} = 0.4\text{V}$		-2	-4	mA
$I_{in(1)}$	Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$			50	$\mu\text{A}$
$I_{in(1)}$	Logical 1 level input current at J or K	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 2.4\text{V}$	0		-1	mA
$I_{in(1)}$	Logical 1 level input current at clock	$V_{CC} = \text{MAX}$ , $V_{in} = 5.5\text{V}$			1	mA

# SIGNETICS DUAL J-K EDGE-TRIGGERED FLIP-FLOP ■ S54H108, N74H108

## ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$I_{in(1)}$	Logical 1 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$				100	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$				1	$\text{mA}$
$I_{in(1)}$	Logical 1 level input current at clear	$V_{CC} = \text{MAX}, V_{in} = 2.4\text{V}$				200	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_{in} = 5.5\text{V}$				1	$\text{mA}$
$I_{OS}$	Short-circuit output current **	$V_{CC} = \text{MAX}, V_{in} = 0$		-40		-100	$\text{mA}$
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$			40	76	$\text{mA}$

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$f_{\text{clock}}$	Maximum input clock frequency	$C_L = 25\text{pF}, R_L = 280\Omega$		40	50		MHz
$t_{pd1}$	Propagation delay time to logical 1 level from preset or clear to output	$C_L = 25\text{pF}, R_L = 280\Omega$			8	12	ns
$t_{pd0}$	Propagation delay time to logical 0 level from preset or clear to output (clock low)	$C_L = 25\text{pF}, R_L = 280\Omega$			23	35	ns
$t_{pd0}$	Propagation delay time to logical 0 level from preset or clear to output (clock high)	$C_L = 25\text{pF}, R_L = 280\Omega$			15	20	ns
$t_{pd1}$	Propagation delay time to logical 1 level from clock to output	$C_L = 25\text{pF}, R_L = 280\Omega$		5	10	15	ns
$t_{pd0}$	Propagation delay time to logical 0 level from clock to output	$C_L = 25\text{pF}, R_L = 280\Omega$		8	16	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

# DIGITAL 54/74 TTL SERIES

## DESCRIPTION

Series 54S/74S Schottky TTL circuits are implemented with full Schottky-barrier-diode clamping to achieve ultra-high speeds previously obtainable only with emitter-coupled logic, yet they retain the desirable features of, and are completely compatible with, most of the popular saturated logic circuits. Schottky TTL circuits currently offer the best speed-power product of any high-speed logic family.

Schottky-barrier-diode clamping prevents transistors from achieving classic saturation and thereby effectively eliminates excess charge storage and subsequent recovery times. These recovery times contribute significantly to overall propagation delays experienced with saturated digital-logic circuits.

Series 54S/74S circuits are completely compatible with the Series 54/74, Series 54H/74H, and Series 54L/74L TTL logic families. Ease of use and compatibility with other TTL families result in flexibility of choice within the four speed-power ranges offered (Series 54/74, 54H/74H, 54L/74L, 54S/74S) to achieve highly efficient system grading to specific performance requirements.

Definitive specifications are provided for operating characteristics over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$  for Series 54S circuits and over the temperature range of  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$  for Series 74S circuits.

## FEATURES

### VERY-HIGH-SPEED, LOW-POWER OPERATION

- 3-ns typical gate propagation delay time
- 19-mW-per-gate power dissipation at 50% duty cycle—speed-power product = 57pJ
- 125-MHz typical J-K flip-flop maximum input clock frequency (d-c coupled)

### EASE OF SYSTEM DESIGN

- fully compatible with Series 54/74, 54H/74H, and 54L/74L TTL (including MSI/LSI), and most DTL
- Schottky-diode-clamped inputs simplify system design
- terminated, controlled-impedance lines not normally required
- low output impedance: provides low AC noise susceptibility drives highly capacitive loads

### IMPROVED CIRCUIT PERFORMANCE

- switching times virtually insensitive to power supply and/or temperature variations
- power dissipation remains relatively low at operating frequencies up to 100 MHz
- high-fan-out: 20 54S/74S loads at the high logic level 10 54S/74S loads at the low logic level
- high DC noise margin—typically 1 volt

## RECOMMENDED OPERATING CONDITIONS

	SERIES 54S CIRCUITS			SERIES 74S CIRCUITS			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Operating Free-Air Temperature, $T_A$	-55		125	0		70	$^{\circ}\text{C}$

## ABSOLUTE MAXIMUM RATINGS (over operating free-air temperature range unless otherwise noted)

Supply Voltage $V_{CC}$	7V
Input Voltage	5.5V
Interrmitter Voltage	5.5V
Output Voltage	7V
Operating Free-Air Temperature Range:	
Series 54S Circuits	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
Series 74S Circuits	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

## NOTES:

1. Voltage values, except intermitter voltage, are with respect to network ground terminal.
2. This is the voltage between two emitters of a multiple-emitter transistor.
3. This is the maximum voltage which should be applied to any open-collector output when it is in the off state.

## UNUSED INPUTS OF POSITIVE-AND/NAND GATES

For optimum switching times and minimum noise susceptibility, unused inputs of AND or NAND gates should be maintained at a voltage greater than 2.7V, but not to exceed the absolute maximum rating of 5.5V. This eliminates the distributed capacitance associated with the floating input emitter, bond wire, and package lead, and ensures that no degradation will occur in the propagation delay times. Some possible ways of handling input emitters are:

- a. Connect unused inputs to an independent supply voltage. Preferably, this voltage should be between 2.7V and 3.5V.
- b. Connect unused inputs to a used input if maximum fan-out of the driving output will not be exceeded. Each additional input presents a full load to the driving output at a high-level voltage but adds no loading at a low-level voltage.
- c. Connect unused inputs to  $V_{CC}$  through a 1-k $\Omega$  resistor so that if a transient which exceeds the 5.5-V maximum rating should occur, the impedance will be high enough to protect the input. One to 25 unused inputs may be connected to each 1-k $\Omega$  resistor.

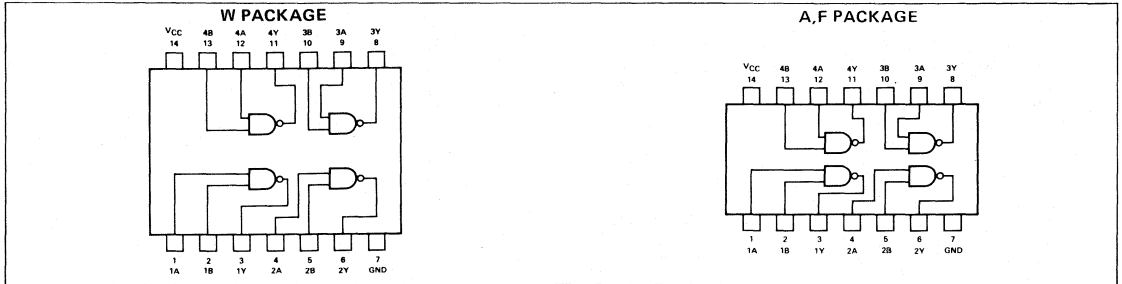
## INPUT-CURRENT REQUIREMENTS

Input-current requirements reflect worst-case  $V_{CC}$  and temperature conditions. Each input of the multiple-emitter input transistors requires a maximum of 2mA out of the input at a low logic level which is defined as 1 normalized load. Each input requires current into the input at a high logic level. This current is 50 $\mu\text{A}$  maximum for each emitter. Currents into the input terminals are specified as positive values.

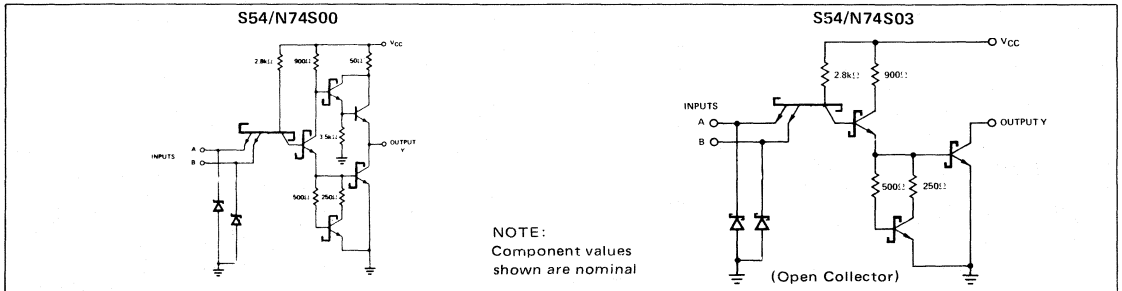
## FAN-OUT CAPABILITY

Fan-out (N) reflects the ability of an output to supply current to a number of normalized loads at a high logic level and to sink current at the low logic level. At the high logic level, each standard output is capable of supplying current to drive 20 Series 54H, 74H, 54S, or 74S loads ( $N_H = 20$ ). Currents out of the output are specified as negative values. At the low logic level, each standard output is capable of sinking current from 10 Series 54H, 74H, 54S, or 74S loads ( $N_L = 10$ ).

### PIN CONFIGURATIONS



### SCHEMATIC (each gate)



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S00			N74S00			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:							
High logic level				20			20
Low logic level				10			10
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted) (74S00)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$V_I$	Input clamp voltage			-1.2	V
$V_{OH}$	High-level output voltage				V
$V_{OL}$	Low-level output voltage			0.5	V
$I_I$	Input current at maximum input voltage			1	mA
$I_{IH}$	High-level input current (each input)			50	μA
$I_{IL}$	Low-level input current (each input)			-2	mA
$I_{OS}$	Short-circuit output current†			-100	mA
$I_{CCH}$	Supply current, high-level output (average per gate)		2.5	4	mA
$I_{CCL}$	Supply current, low-level output (average per gate)		5	9	mA



# SIGNETICS QUADRUPLE 2-INPUT POSITIVE NAND GATE ■ S54S00, S54S03, N74S00, N74S03

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$  (74S00)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$ , $R_L = 280\Omega$	NOTE 1	2	3	4.5	ns
		$C_L = 50pF$ , $R_L = 280\Omega$			4.5		
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15pF$ , $R_L = 280\Omega$	NOTE 1	2	3	5	ns
		$C_L = 50pF$ , $R_L = 280\Omega$			5		

S54/N74S03

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		MIN	TYP**	MAX	UNIT	
$V_{IH}$	High-level input voltage	2			V	
$V_{IL}$	Low-level input voltage			0.8	V	
$V_I$	Input clamp voltage			-1.2	V	
$I_{OH}$	High-level output current	$V_{CC} = MIN$ , $V_{OH} = 5.5V$	$I_I = -18mA$ , $V_{IL} = 0.8V$ ,	250	$\mu A$	
$V_{OL}$	Low-level output voltage	$V_{CC} = MIN$ , $I_{OL} = 20mA$	$V_{IH} = 2V$ ,	0.5	V	
$I_I$	Input current at maximum input voltage	$V_{CC} = MAX$ ,	$V_I = 5.5V$	1	mA	
$I_{IH}$	High-level input current (each input)	$V_{CC} = MAX$ ,	$V_I = 2.7V$	50	$\mu A$	
$I_{IL}$	Low-level input current (each input)	$V_{CC} = MAX$ ,	$V_I = 0.5V$	-2	mA	
$I_{CCH}$	Supply current, high-level output (average per gate)	$V_{CC} = MAX$ ,	All inputs at 0V	1.5	3.3	mA
$I_{CCL}$	Supply current, low-level output (average per gate)	$V_{CC} = MAX$ ,	All inputs at 5V	5	9	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$ , $R_L = 280\Omega$	NOTE 1	2	5	5ns	ns
		$C_L = 50pF$ , $R_L = 280\Omega$			4.5		
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15pF$ , $R_L = 280\Omega$	NOTE 1	2	4.5	7	ns
		$C_L = 50pF$ , $R_L = 280\Omega$			7		

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

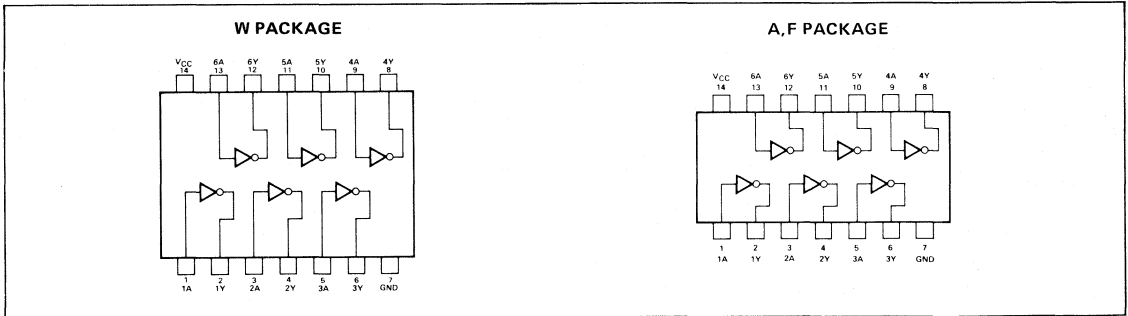
† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

NOTE 1: Load circuit and waveforms are shown on page 2-293

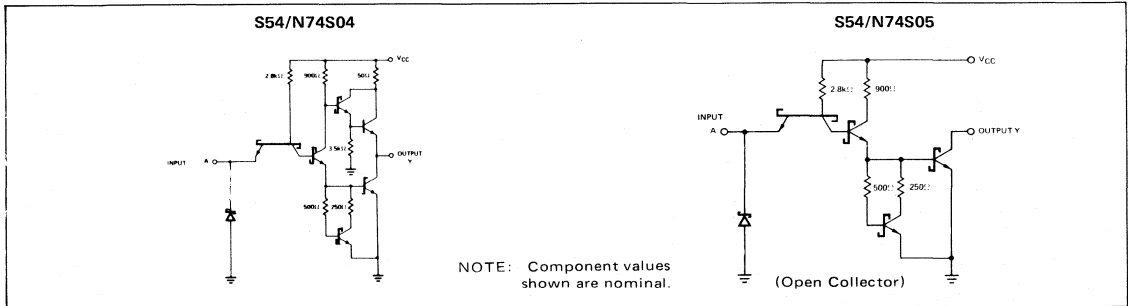
S54S04-A,F,W • S54S05-A,F,W • N74S04-A,F,W • N74S05-A,F

DIGITAL 54/74 TTL SERIES

### PIN CONFIGURATIONS



### SCHEMATIC (each gate)



### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S04			N74S04			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level Low logic level						
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C

### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted) (74S04)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$V_I$	Input clamp voltage			-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_{OH} = -1\text{mA}$	2.5	3.4	V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, I_{OL} = 20\text{mA}$	2.7	3.4	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$		1	mA
$I_{IH}$	High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$		50	μA
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$		-2	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX}$	-40	-100	mA
$I_{CCH}$	Supply current, high-level output (average per gate)	$V_{CC} = \text{MAX},$ All inputs at 0V	2.5	4	mA
$I_{CCL}$	Supply current, low-level output (average per gate)	$V_{CC} = \text{MAX},$ All inputs at 5V	5	9	mA

## SIGNETICS HEX INVERTER ■ S54S04, S54S05, N74S04, N74S05

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}$ ,	$R_L = 280 \Omega$	NOTE 1	2	3	4.5	ns
		$C_L = 50 \text{ pF}$ ,	$R_L = 280 \Omega$			4.5		
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}$ ,	$R_L = 280 \Omega$		2	3	5	ns
		$C_L = 50 \text{ pF}$ ,	$R_L = 280 \Omega$			5*		

S54/N74S05

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}$ ,	$I_I = -18\text{mA}$			-1.2	V
$I_{OH}$	High-level output current	$V_{CC} = \text{MIN}$ ,	$V_{IL} = 0.8V$ ,			250	$\mu A$
$V_{OL}$	Low-level output voltage	$V_{OH} = 5.5V$				0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MIN}$ ,	$V_{IH} = 2V$ ,				
$I_{IH}$	High-level input current (each input)	$I_{OL} = 20\text{mA}$				1	mA
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MAX}$ ,	$V_I = 5.5V$			50	$\mu A$
$I_{CCH}$	Supply current, high-level output (average per gate)	$V_{CC} = \text{MAX}$ ,	$V_I = 2.7V$			-2	mA
$I_{CCL}$	Supply current, low-level output (average per gate)	$V_{CC} = \text{MAX}$ ,	$V_I = 0.5V$		1.5	3.3	mA
		$V_{CC} = \text{MAX}$ ,	All inputs at 0V		5	9	mA

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}$ ,	$R_L = 280 \Omega$	NOTE 1	2	5	5ns	
		$C_L = 50 \text{ pF}$ ,	$R_L = 280 \Omega$			4.5		
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}$ ,	$R_L = 280 \Omega$		2	4.5	7	ns
		$C_L = 50 \text{ pF}$ ,	$R_L = 280 \Omega$			7		

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

**NOTES:**

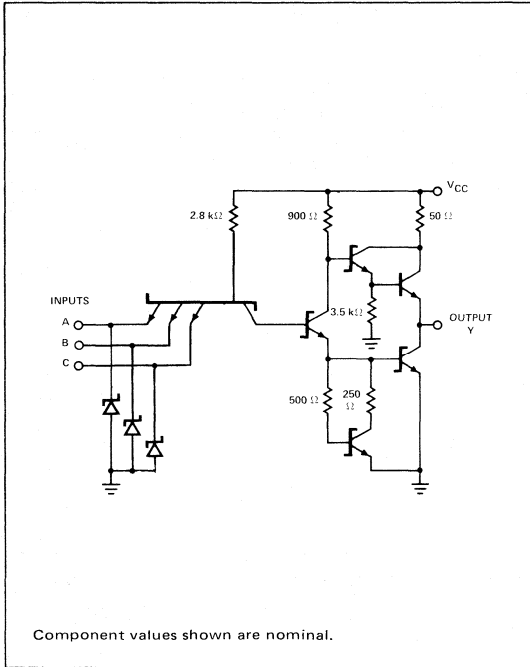
A. The pulse generator has the following characteristics:  $V_{in(1)} = 3V$ ,  $V_{in(0)} = 0V$ ,  $t_1 = t_0 = 2.5\text{ns}$ ,  $\text{PRR} = 1 \text{ MHz}$ , duty cycle = 50%, and  $Z_{out} \approx 50\Omega$ .

B. Inputs not under test are at 2.7V.

C.  $C_L$  includes probe and jig capacitance.

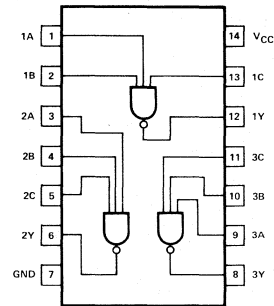
NOTE 1: Load circuit and waveforms are shown on page 2-293

### SCHEMATIC DIAGRAM



### PIN CONFIGURATION

SN54S10, SN74S10 TRIPLE 3-INPUT NAND GATES



Positive logic:  $Y = \overline{ABC}$

### Note:

The 54/74S10 use the same specification as the S00/04/20.

### RECOMMENDED OPERATING CONDITIONS

		S54S10			S74S10			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level				20			
	Low logic level				10			
Operating free-air, $T_A$		-55	125		0	70		°C

# SIGNETICS TRIPLE 3-INPUT POSITIVE NAND GATE ■ S54S10, N74S10

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input Clamp Voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$				-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$	Series 54S	2.5	3.4		V
			Series 74S	2.7	3.4		V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 20 \text{ mA}$				0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$				1	mA
$I_{IH}$	High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$				50	$\mu\text{A}$
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$				-2	mA
$I_{OS}$	Short-circuit output current‡	$V_{CC} = \text{MAX}$		-40		-100	mA
$I_{CCH}$	Supply current, high-level output (average per gate)	$V_{CC} = \text{MAX},$ All inputs at 0 V			2.5	4	mA
$I_{CCL}$	Supply current, low-level output (average per gate)	$V_{CC} = \text{MAX},$ All inputs at 5 V			5	9	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

‡Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	NOTE 1	2	3	4.5	ns
		$C_L = 50 \text{ pF}, R_L = 280 \Omega$			4.5		
$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$		2	3	5	ns
		$C_L = 50 \text{ pF}, R_L = 280 \Omega$			5		

NOTE 1: Load circuit and waveforms are shown on page 2-293

### FEATURES

#### N74S11 ACTIVE PULL-UP

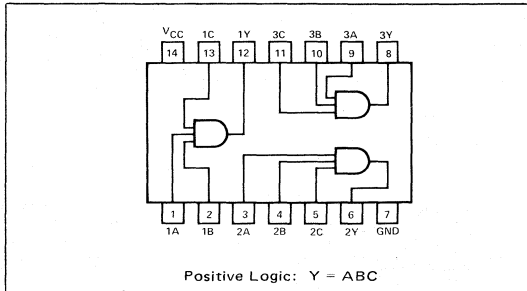
- TYPICAL PROPAGATION TIME
- TYPICAL POWER DISSIPATION AT 50% DUTY CYCLE

5 ns at  $C_L = \text{pF}$   
32 mW PER GATE

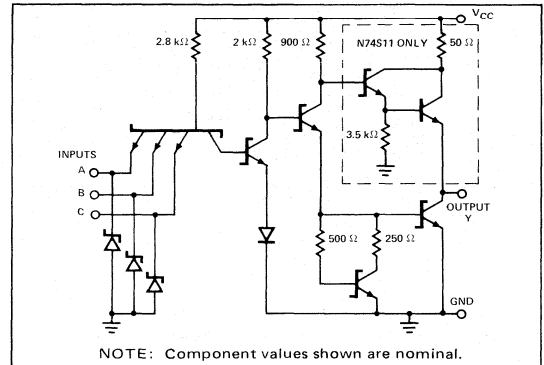
#### N74S15 OPEN-COLLECTOR

- TYPICAL PROPAGATION TIME
- TYPICAL POWER DISSIPATION AT 50% DUTY CYCLE

6 ns at  $C_L = 15 \text{ pF}$   
29 mW PER GATE



### SCHEMATIC (each gate)



NOTE: Component values shown are nominal.

### RECOMMENDED MAXIMUM FAN-OUT FROM EACH OUTPUT

	N74S11	N74S15
Loads at a high logic level	20	
Loads at a low logic level	10	10

### ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	N74S11		N74S15		UNIT
		MIN	TYP** MAX	MIN	TYP** MAX	
$V_{IH}$ High-level input voltage		2		2		V
$V_{IL}$ Low-level input voltage			0.8		0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$		-1.2		-1.2	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OH} = -1 \text{ mA}$	2.7	3.4			V
$I_{OH}$ High-level output current	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{OH} = 5.5 \text{ V}$			250		$\mu\text{A}$
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OL} = 20 \text{ mA}$		0.5		0.5	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$		1		1	mA
$I_{IH}$ High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$		50		50	$\mu\text{A}$
$I_{IL}$ Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$		-2		-2	mA
$I_{OS}$ Short-circuit output current $\ddagger$	$V_{CC} = \text{MAX}$	-40	-100			mA
$I_{CCH}$ Supply current, high-level output (average per gate)	$V_{CC} = \text{MAX}, \text{ All inputs at } 5 \text{ V}$	4.5	8	3.5	6.5	mA
$I_{CCL}$ Supply current, low-level output (Average per gate)	$V_{CC} = \text{MAX}, \text{ All inputs at } 0 \text{ V}$	8	14	8	14	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable series on the second page of this section.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

$\ddagger$ Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

### SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}, N = 10$

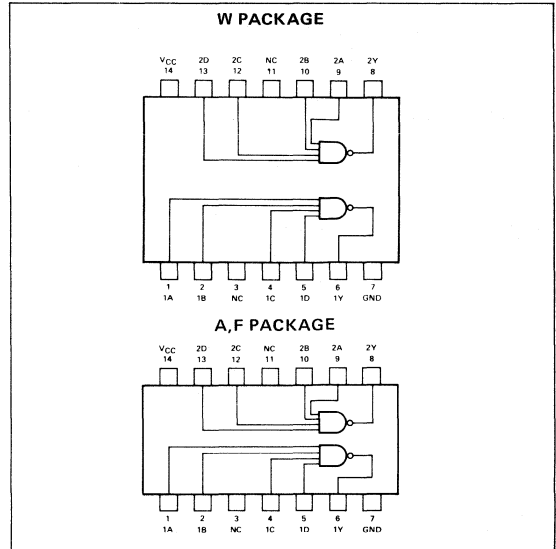
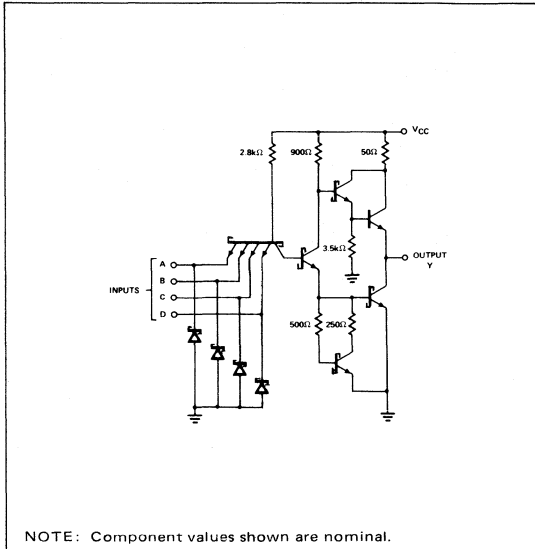
PARAMETER	TEST CONDITIONS NOTE 1	N74S11			N74S15			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
$t_{PLH}$ Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2.5	4.5	7	2.5	5.5	8.5	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$		6		8.5			
$t_{PHL}$ Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2.5	5	7.5	2.5	6	9	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$		7.5		8			

NOTE 1: Load circuits and waveforms are shown on page 2-293

S54S20-A,F,W • N74S20-A,F

DIGITAL 54/74 TTL SERIES

**SCHEMATIC (each gate)**



**RECOMMENDED OPERATING CONDITIONS**

PARAMETER	S54S20			N74S20			UNIT	
	MIN	NOM	MAX	MIN	NOM	MAX		
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V	
Normalized Fan-Out from each Output, N:	High logic level						20	
	Low logic level						10	
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C	

**ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)**

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage				0.8
$V_I$	Input clamp voltage				-1.2
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_{OH} = -1\text{mA}$	2.5	3.4	V
		$V_{CC} = \text{MIN}, I_{OH} = -1\text{mA}$	2.7	3.4	V
$V_{OL}$	Low-level output voltage				0.5
$I_I$	Input current at maximum input voltage				1
$I_{IH}$	High-level input current (each input)				50
$I_{IL}$	Low-level input current (each input)				-2
$I_{OS}$	Short-circuit output current †				-100
ICCH	Supply current, high-level output (average per gate)				4
		$V_{CC} = \text{MAX},$ All inputs at 0V	-40	2.5	4
ICCL	Supply current, low-level output (average per gate)				9
		$V_{CC} = \text{MAX},$ All inputs at 5V	5	9	mA

# SIGNETICS DUAL 4-INPUT POSITIVE NAND GATE ■ S54S20, N74S20

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output	$C_L = 15pF$ ,	$R_L = 280\Omega$	NOTE 1	2	3	4.5	ns
		$C_L = 50pF$ ,	$R_L = 280\Omega$			4.5		
t <sub>PHL</sub>	Propagation delay time, high-to-low-level output	$C_L = 15pF$ ,	$R_L = 280\Omega$		2	3	5	ns
		$C_L = 50pF$ ,	$R_L = 280\Omega$			5		

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

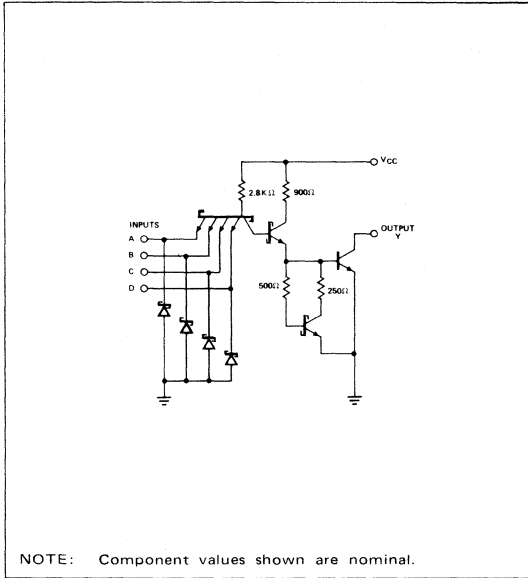
NOTE 1: Load circuits and waveforms are shown on page 2-293



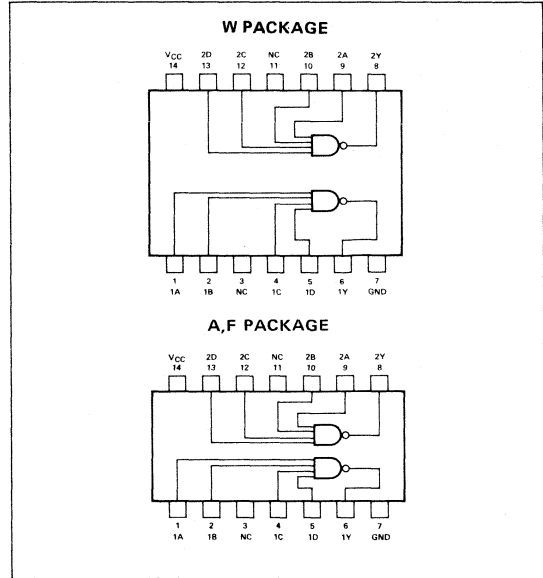
S54S22-A, F, W • N74S22-A, F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S22			N74S22			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from any Output, N			10			10	
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{IH}$ High-level input voltage			2		V
$V_{IL}$ Low-level input voltage				0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18\text{mA}$			-1.2	V
$I_{OH}$ High-level output current	$V_{CC} = \text{MIN}, V_{OH} = 5.5\text{V}$			250	$\mu\text{A}$
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, I_{OL} = 20\text{mA}$			0.5	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$ High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$			50	$\mu\text{A}$
$I_{IL}$ Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$			-2	mA
$I_{CCH}$ Supply current, high-level output (average per gate)	$V_{CC} = \text{MAX},$ All inputs at 0V		1.5	3.3	mA
$I_{CCL}$ Supply current, low-level output (average per gate)	$V_{CC} = \text{MAX},$ All inputs at 5V		5	9	mA

# SIGNETICS DUAL 4-INPUT POSITIVE NAND GATE ■ S54S22, N74S22

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 10$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output	$C_L = 15pF$ , $C_L = 50pF$	$R_L = 280\Omega$ , $R_L = 280\Omega$	2	5 7.5	7.5	ns
	$t_{PHL}$	Propagation delay time, high-to-low-level output	$C_L = 15pF$ , $C_L = 50pF$		$R_L = 280\Omega$ , $R_L = 280\Omega$		
NOTE 1							

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

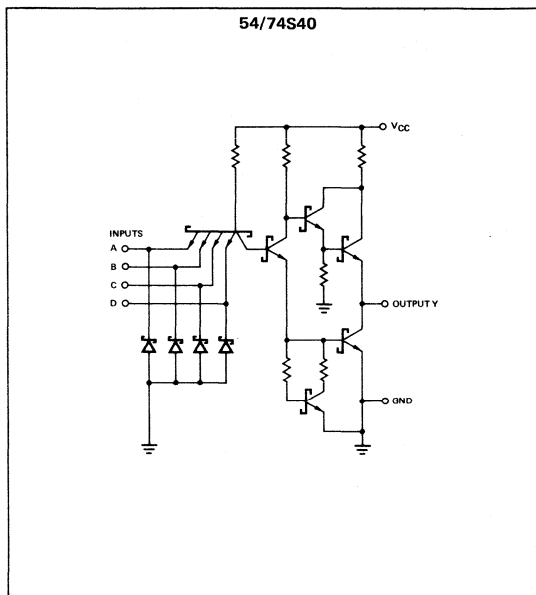
\*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .

NOTE 1: Load circuit and waveforms are shown on page 2-293

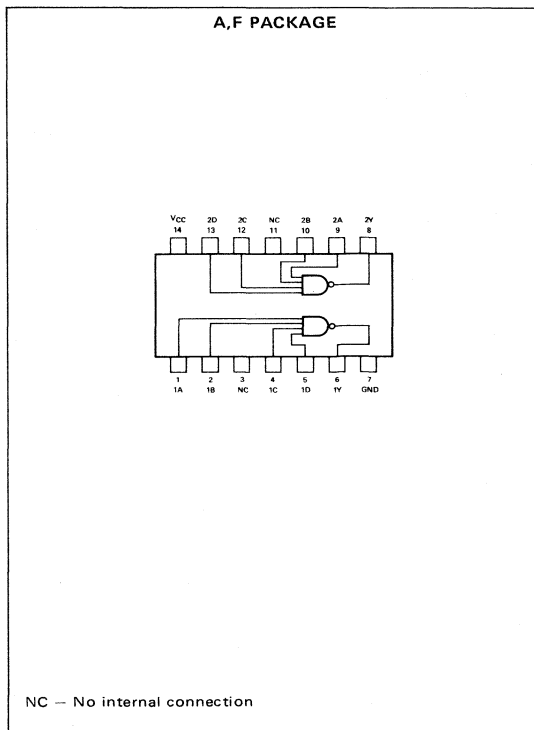
S54S40—A,F,W • S54S140—A,F,W • N74S40—A,F • N74S140—A,F

DIGITAL 54/74 TTL SERIES

SCHEMATIC (each gate)



PIN CONFIGURATIONS



NC — No internal connection

RECOMMENDED MAXIMUM FAN-OUT FROM EACH OUTPUT

Loads at a high logic level	60
Load at a low logic level	30

ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN},$ $V_{CC} = \text{MIN},$ $I_{OH} = -3\text{mA}$	$I_I = -18\text{mA}$ $V_{IL} = 0.8\text{V},$	2.5	3.4	-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN},$ $R_O = 50\Omega \text{ To GND}$	$V_I = 0.5\text{V},$ $V_{IH} = 2\text{V},$	2.7	3.4		V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN},$ $I_{OL} = 60\text{mA}$		2		0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX},$	$V_I = 5.5\text{V}$			1	mA
$I_{IH}$	High-level input current (each input)	$V_{CC} = \text{MAX},$	$V_I = 2.7\text{V}$			100	$\mu\text{A}$
$I_{IL}$	Low-level input current (each input)	$V_{CC} = \text{MAX},$	$V_I = 0.5\text{V}$			-4	mA
$I_{OS}$	Short-circuit output current †	$V_{CC} = \text{MAX}$		-50		-225	mA
$I_{CCH}$	Supply current, high-level output (average per gate)	$V_{CC} = \text{MAX},$	All inputs at 0V		5	9	mA
$I_{CCL}$	Supply current, low-level output (average per gate)	$V_{CC} = \text{MAX},$	All inputs at 5V		12.5	22	mA

# SIGNETICS DUAL 4-INPUT POSITIVE NAND BUFFERS/LINE DRIVERS ■ S54/N74S40, S54/N74S140

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ ,  $N = 30$

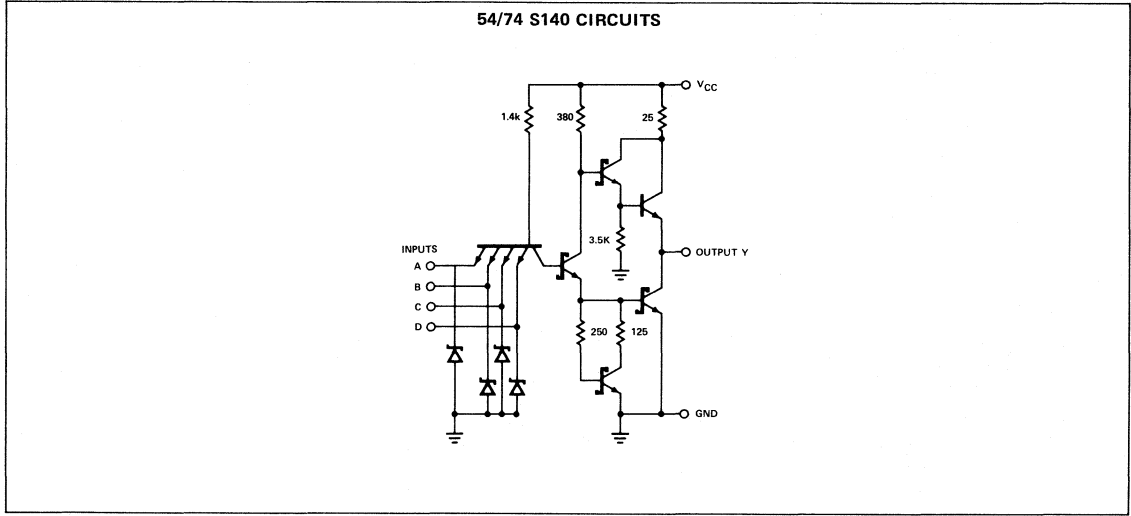
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation delay time, low-to-high-level output $C_L = 50pF$ , $R_L = 93\Omega$	2	4	6.5	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output $C_L = 150pF$ , $R_L = 93\Omega$	2	6	6.5	ns
	$C_L = 50pF$ , $R_L = 93\Omega$		4	6.5	ns
	$C_L = 150pF$ , $R_L = 93\Omega$		6	6.5	ns

NOTE 1

- \* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable series on the second page of this section.
- \*\* All typical values are at  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ .
- † Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed 100 milliseconds.

NOTE 1: Load circuit and waveforms are shown on page 2-293

## SCHEMATIC



## DIGITAL 54/74 TTL SERIES

### FEATURES

#### N74S64 ACTIVE PULL-UP

- TYPICAL PROPAGATION TIME
- TYPICAL POWER DISSIPATION AT 50% DUTY CYCLE

3.5 ns at  $C_L = 15 \text{ pF}$   
39 mW

#### N74S65 OPEN COLLECTOR

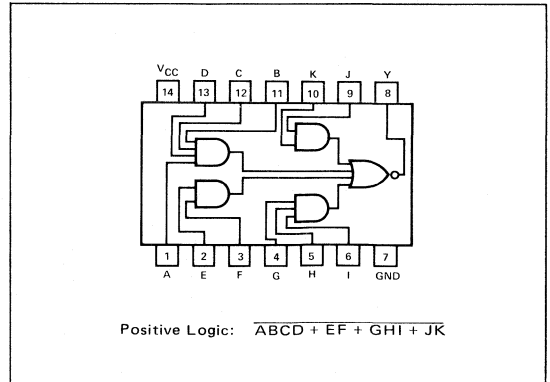
- TYPICAL PROPAGATION TIME
- TYPICAL POWER DISSIPATION AT 50% DUTY CYCLE

5 ns at  $C_L = 15 \text{ pF}$   
36 mW

### RECOMMENDED MAXIMUM FAN-OUT FROM EACH OUTPUT

	N74S64	N74S65
Loads at a high logic level	20	
Loads at a low logic level	10	10

### PIN CONFIGURATIONS



### ELECTRICAL CHARACTERISTICS (over operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	N74S64			N74S65			UNIT
		MIN	TYP**	MAX	MIN	TYP**	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.2			-1.2	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$ (N74S64)	2.7	3.4					V
$I_{OH}$ High-level output current	$V_{CC} = \text{MIN}, V_{IH} = 0.8 \text{ V}, V_{OH} = 5.5 \text{ V}$					250		$\mu\text{A}$
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 2 \text{ V}, I_{OL} = 20 \text{ mA}$			0.5		0.5		V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1		1		mA
$I_{IH}$ High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$			50		50		$\mu\text{A}$
$I_{IL}$ Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$			-2		-2		mA
$I_{OS}$ Short-circuit output current ‡	$V_{CC} = \text{MAX}$	-40		-100				mA
$I_{CCH}$ Supply current, high-level output	$V_{CC} = \text{MAX}$ , See Note 1		7	12.5		6	11	mA
$I_{CCL}$ Supply current, low-level output	$V_{CC} = \text{MAX}$ , See Note 2		8.5	16		8.5	16	mA

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}$ .

‡ Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

NOTES: 1.  $I_{CCH}$  is measured with all inputs grounded, and the outputs open.

2.  $I_{CCL}$  is measured with all inputs of one gate at 5 V, the remaining inputs grounded, and the outputs open.

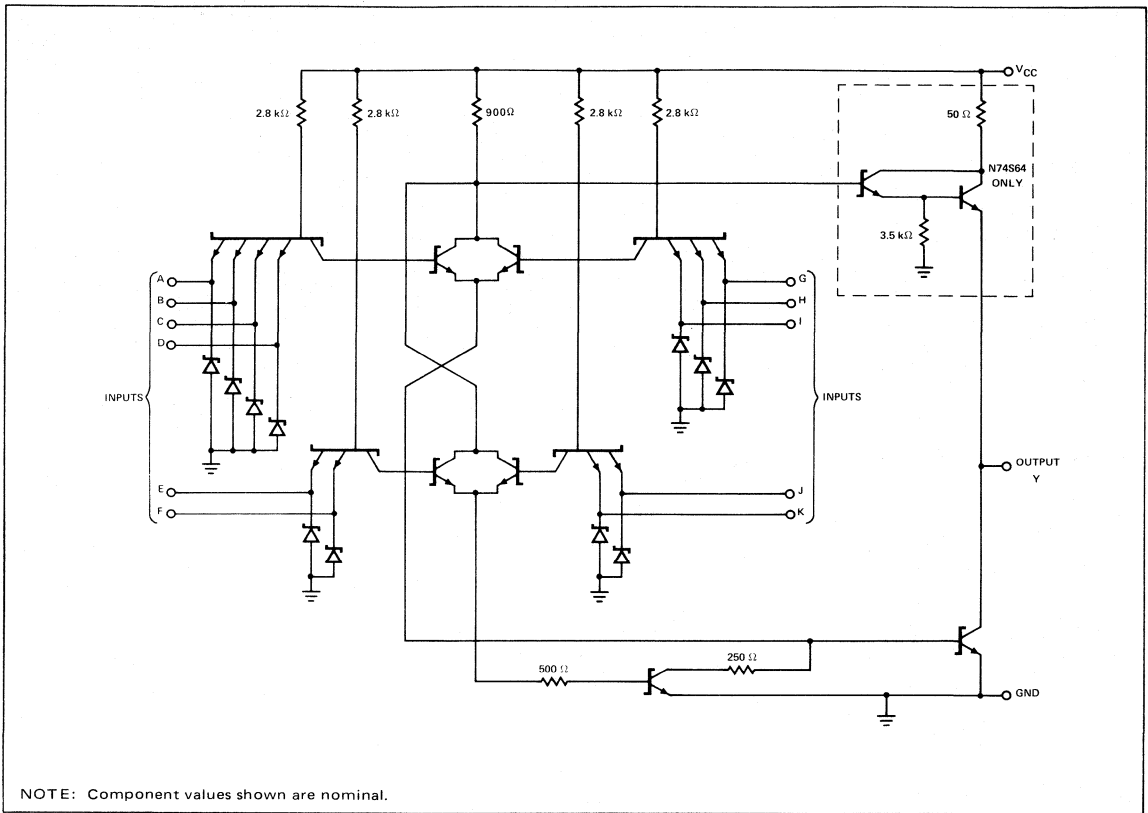
### SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}, N = 10$

PARAMETER	TEST CONDITIONS NOTE 3	N74S64			N74S65			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	
$t_{PLH}$ Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2	3.5	5.5	2	5	7.5	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$		5			8		
$t_{PHL}$ Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2	3.5	5.5	2	5.5	3.5	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$		5.5			6.5		

NOTE 3: Load circuit and waveforms are shown on page 2-293

SIGNETICS 4-2-3-2-INPUT AND-OR GATES ■ N74S64, N74S65

SCHEMATIC



### DIGITAL 54/74 TTL SERIES

#### DESCRIPTION

These monolithic dual edge-triggered flip-flops utilize Schottky TTL circuitry to produce very high speed D-type flip-flops. Each flip-flop has individual clear and preset inputs, and also complementary Q outputs.

Information at input D is transferred to the Q output on the positive going edge of the clock pulse. Clock triggering occurs at a voltage level of the clock pulse and is not directly related to the transition time of the positive going pulse. When the clock input is at either the high or low level, the D-input signal has no effect.

These circuits are fully compatible for use with most TTL or DTL circuits. A full fan-out to 10-normalized series 54S/74S loads is available from each of the outputs at low logic level. At a high logic level, a fan-out of 20 is available to facilitate tying unused inputs to used inputs. Maximum clock frequency is 75 megahertz, with a typical power dissipation of 75 milliwatts per flip-flop.

The N74S74 is characterized for operation from 0°C to 70°C.

Typical Maximum Input Clock Frequency 90 MHz  
Typical Power Dissipation 75 mW per Flip-Flop

#### TRUTH TABLE (Each Flip-Flop)

INPUT	OUTPUT	
	Q	$\bar{Q}$
D	Q	$\bar{Q}$
L	L	H
H	H	L

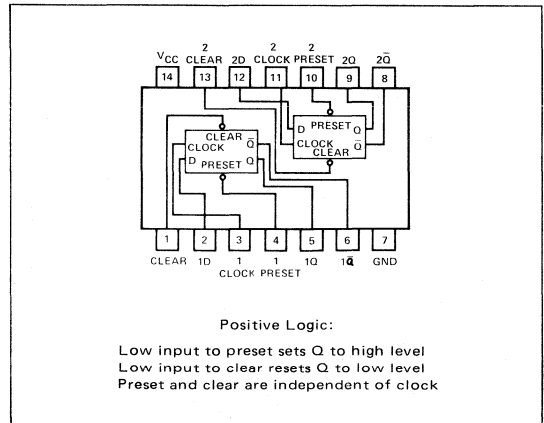
H = High level, L = Low level

NOTES: A.  $t_n$  = bit time before clock pulse  
B.  $t_{n+1}$  = bit time after clock pulse

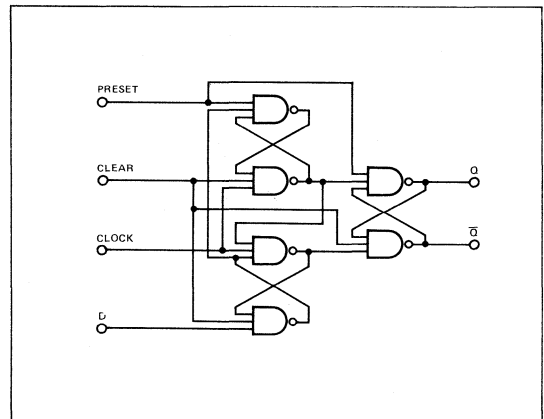
#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	MIN	NOM	MAX	UNIT
Supply voltage, $V_{CC}$	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20	
	Low logic level		10	
Clock frequency, $f_{clock}$		70		MHz
Width of clock pulse, $t_w$ (clock)		7		ns
Width of preset pulse, $t_w$ (preset)		7		ns
Width of clear pulse, $t_w$ (clear)		7		ns
Input set-up time, $t_{setup}$	High level data	10		ns
	Low level data	12		
Input hold time, $t_{hold}$	0			ns
Operating free-air temperature, $T_A$	0		70	°C

#### PIN CONFIGURATION



#### FUNCTIONAL BLOCK DIAGRAM (EACH FLIP-FLOP)



# SIGNETICS DUAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS ■ S54S74,N74S74

## ELECTRICAL CHARACTERISTICS

PARAMETER		TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
V <sub>IH</sub>	High level input voltage		2			V
V <sub>IL</sub>	Low level input voltage				0.8	V
V <sub>I</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA			-1.2	V
V <sub>OH</sub>	High level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V	2.7	3.4		V
		V <sub>IL</sub> = 0.8, I <sub>OL</sub> = 20 mA				
V <sub>OL</sub>	Low level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V			0.5	V
		V <sub>IL</sub> = 0.8, I <sub>OL</sub> = 20 mA				
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V			1	mA
I <sub>IH</sub>	High level input current	V <sub>CC</sub> = MAX, D input			50	μA
		V <sub>I</sub> = 2.7 V Clock or Preset			100	
		Clear			150	
I <sub>IL</sub>	Low level input current	V <sub>CC</sub> = MAX, D input			-2	mA
		V <sub>I</sub> = 0.5 V Clock or Preset			-4	
		Clear			-6	
I <sub>OS</sub>	Short circuit output current‡	V <sub>CC</sub> = MAX	-40		-100	mA
I <sub>CC</sub>	Supply Current	V <sub>CC</sub> = MAX, See Note 1		30		mA

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

‡ Not more than one output should be shorted at a time, and duration of the short circuit test should not exceed one second.

## SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C, N = 10

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
f <sub>max</sub>	Maximum clock frequency	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 280 Ω  <b>NOTE 1</b>		90		MHz
t <sub>PLH</sub>	Propagation delay time, low-to-high level output, from clear or preset			5		ns
t <sub>PHL</sub>	Propagation delay time, high-to-low level output, from clear or preset			8		ns
t <sub>PLH</sub>	Propagation delay time, low-to-high level output, from clock			7		ns
t <sub>PHL</sub>	Propagation delay time, high-to-low level output, from clock			7		ns

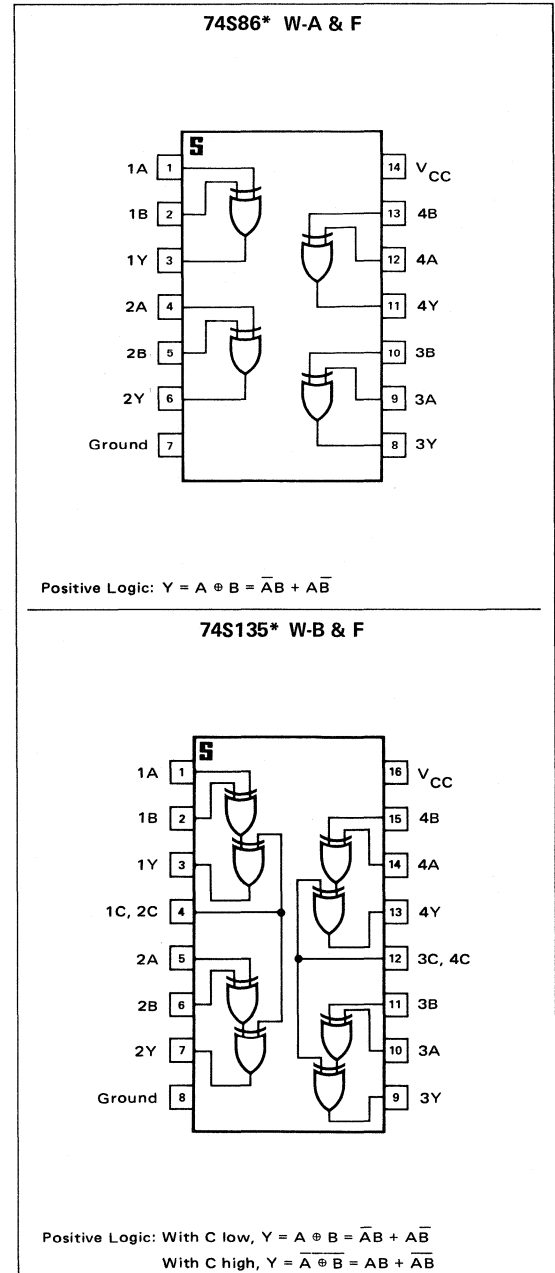
NOTE 1: Load circuit and test waveforms are shown on page 2-293



### FEATURES

- FULLY COMPATIBLE WITH MOST TTL AND TTL MSI CIRCUITS
- FULLY SCHOTTKY CLAMPING REDUCES DELAY TIMES:
  - 7 ns Typical      54S86\*/74S86
  - 8 ns Typical      54S135\*/74S135
- 54S135\*, 74S135 CAN OPERATE AS EXCLUSIVE-OR GATE (C INPUT LOW) OR AS EXCLUSIVE-NOR GATE (C INPUT HIGH)

### PIN CONFIGURATION (Top View)\*



Positive Logic:  $Y = A \oplus B = \bar{A}B + A\bar{B}$

Positive Logic: With C low,  $Y = A \oplus B = \bar{A}B + A\bar{B}$   
With C high,  $Y = \bar{A} \oplus B = AB + \bar{A}\bar{B}$

\*Pin assignments same for all packages.

### ABSOLUTE MAXIMUM RATINGS

Supply voltage (see Note 1)	7 V
Input voltage	5.5 V
Operating free-air temperature range:	
54S86*, 54S135* Circuits	-55°C to 125°C
74S86, 74S135 Circuits	0°C to 70°C
Storage temperature range	-65°C to 150°C

#### NOTE:

1. All voltage values are with respect to network ground terminal.

### FUNCTION TABLE 54S86\*, 74S86

INPUTS		OUTPUT
A	B	Y
L	L	L
L	H	H
H	L	H
H	H	L

H = High level, L = Low level

### FUNCTION TABLE 54S135\*, 74S135

INPUTS			OUTPUT
A	B	C	Y
L	L	L	L
L	H	L	H
H	L	L	H
H	H	L	L
L	L	H	H
L	H	H	L
H	L	H	L
H	H	H	H

H = High level, L = Low level

**SIGNETICS QUAD EXCLUSIVE-OR, EXCLUSIVE-OR/NOR GATES ■ S54/N74S86, S54/N74S135**

**ELECTRICAL CHARACTERISTICS** (Over recommended operating free-air temperature range. Unless otherwise noted.)

PARAMETER	TEST CONDITIONS*		MIN.	TYP.**	MAX.	UNIT
$V_{IH}$ High level input voltage			2			V
$V_{IL}$ Low-level input voltage					0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18\text{mA}$				-1.2	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, I_I = -18\text{mA}$	Series 54S*	2.5	3.4		V
	$V_{IL} = 0.8\text{V}, I_{OH} = -1\text{mA}$	Series 74S*	2.7	3.4		
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V},$ $V_{IL} = 0.8\text{V}, I_{OL} = 20\text{mA}$				0.5	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$				1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$				50	$\mu\text{A}$
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$				-2	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = \text{MAX}$		-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ See Note	54S86*				mA
		74S86				
		54S135*				
		74S135				

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

NOTE:

$I_{CC}$  is measured with the inputs grounded and the outputs open.

**RECOMMENDED OPERATING CONDITIONS**

		54S86*		54S135*		74S86		74S135		UNIT
		MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	MIN.	NOM.	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25			V
Normalized fan-out from each output, N	High logic level			20					20	
	Low logic level			10					10	
Operating free-air temperature, $T_A$		-55		125	0				70	$^\circ\text{C}$

\* Full military version to be announced.

**SIGNETICS QUAD EXCLUSIVE-OR, EXCLUSIVE-OR/NOR GATES ■ S54/N74S86, S54/N74S135**

SWITCHING CHARACTERISTICS  $V_{CC} = 5V, T_A = 25^\circ C, N = 10$

PARAMETER*	FROM (INPUT)	TEST CONDITIONS		SN54S86*, SN74S86			SN54S135*, SN74S135			UNIT
				MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
$t_{PLH}$ $t_{PHL}$	A or B	B or A = L, C = L**	$C_L = 15 \text{ pF},$ $R_I = 280\Omega$	7	10.5		8.5	13	ns	
				6.5	10		11	15		
$t_{PLH}$ $t_{PHL}$	A or B	B or A = H, C = L**		7	10.5		8	12	ns	
				6.5	10		9	13.5		
$t_{PLH}$ $t_{PHL}$	A or B	B or A = L, C = H					10	15	ns	
							6.5	10		
$t_{PLH}$ $t_{PHL}$	A or B	B or A = H, C = H				8.5	12	ns		
						7	11			
$t_{PLH}$ $t_{PHL}$	C	A = B				8	12	ns		
						9.5	14.5			
$t_{PLH}$ $t_{PHL}$	C	A ≠ B				7.5	11.5	ns		
						8	12			

\*  $t_{PLH}$  = Propagation delay time, low to high level output.

$t_{PHL}$  = Propagation delay time, high-to-low-level output.

\*\* References to C input are applicable to 54S135 and 74S135 only.

† Full military version to be announced.

S54S112-B,F,W • N74S112-B

DIGITAL 54/74 TTL SERIES

### DESCRIPTION

These monolithic dual J-K flip-flops feature individual J, K, clock, and asynchronous preset and clear inputs to each flip-flop. When the clock goes high the inputs are enabled and data will be accepted. The logic level of the J and K inputs may be allowed to change when the clock pulse is high and the bistable will perform according to the truth table as long as minimum setup and hold times are observed. Input data are transferred to the outputs on the negative-going edge of the clock pulse.

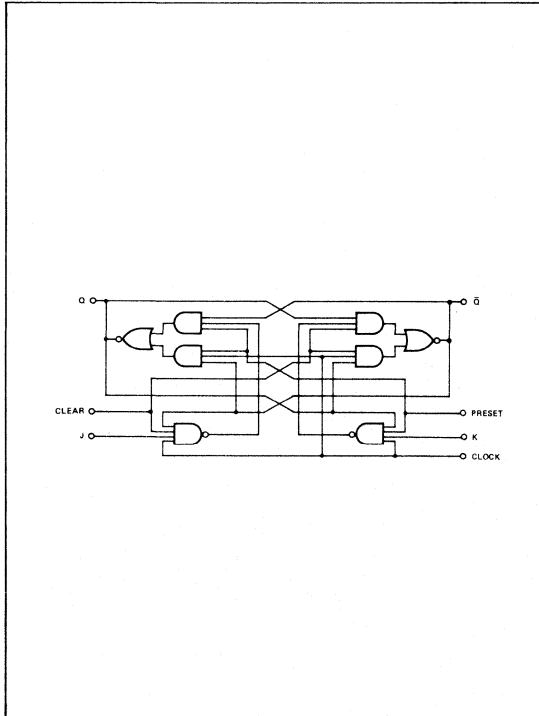
### TRUTH TABLE

$t_n$		$t_{n+1}$
J	K	Q
L	L	$Q_n$
L	H	L
H	L	H
H	H	$\overline{Q_n}$

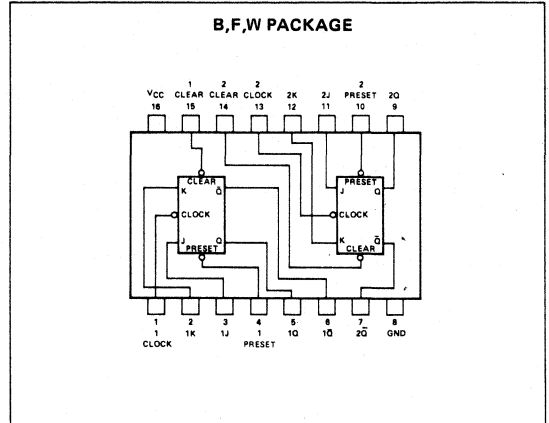
#### NOTES:

- A.  $t_n$  = bit time before clock pulse
- B.  $t_{n+1}$  = bit time after clock pulse

### LOGIC DIAGRAM (each flip-flop)



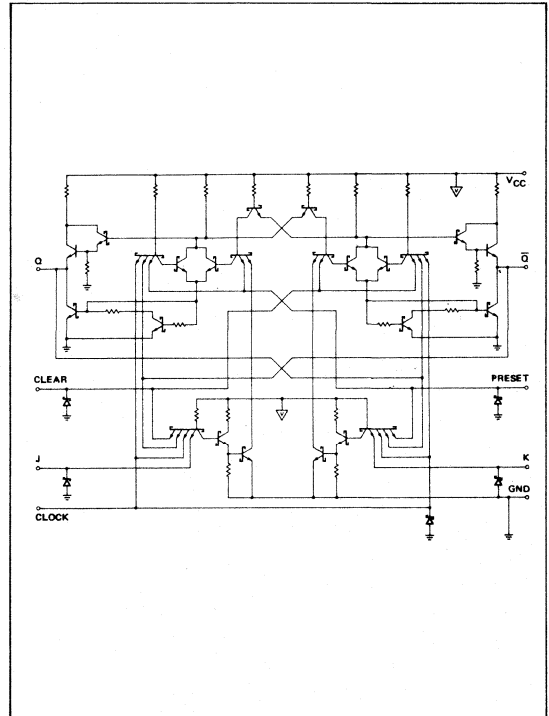
### PIN CONFIGURATIONS



### POSITIVE LOGIC

- positive logic: Low input to preset sets Q to high level.
- Low input to clear resets Q to low level.
- Clear and preset are independent of clock.

### SCHEMATIC (each flip-flop)



# SIGNETICS DUAL J-K EDGE-TRIGGERED FLIP-FLOP ■ S54S112, N74S112

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S112			N74S112			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level			High logic level			
	Low logic level			Low logic level			
Input Clock Frequency, $f_{clock}$	0		80	0		80	MHz
Width of Clock Pulse, $t_{w(clock)}$	6			6			ns
Width of Preset Pulse, $t_{w(preset)}$	8			8			ns
Width of Clear Pulse, $t_{w(clear)}$	8			8			ns
Input Setup Time, $t_{setup}$ (See Note 1)	3			3			ns
Input Hold Time, $t_{hold}$ (See Note 2)	0			0			ns
Operating Free-Air Temperature, $T_A$	-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP **	MAX	UNIT
$V_{IH}$	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
$V_I$	Input clamp voltage			-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_I = -18\text{mA}$			V
		$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, I_{OH} = -1\text{mA}$	2.5	3.4	V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 0.8\text{V}, I_{OL} = 20\text{mA}$	2.7	3.4	V
		$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 20\text{mA}$			0.5
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$		1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$		50	$\mu\text{A}$
		J or K input Clock, preset, or clear		100	$\mu\text{A}$
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$		-1.6	mA
		J or K input Clock Preset or clear		-4 -7	mA
$I_{OS}$	Short-circuit output current†	$V_{CC} = \text{MAX}$		-40	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ , See Note 3	30	50	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum clock frequency	80	125		MHz
$t_{PLH}$	Propagation delay time, low-to-high-level output, from clear or preset	2	4	7	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output, from clear or preset	$C_L = 15\text{pF}, R_L = 280\Omega$	5	7	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output, from clock	NOTE 4	4	7	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output, from clock		5	7	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

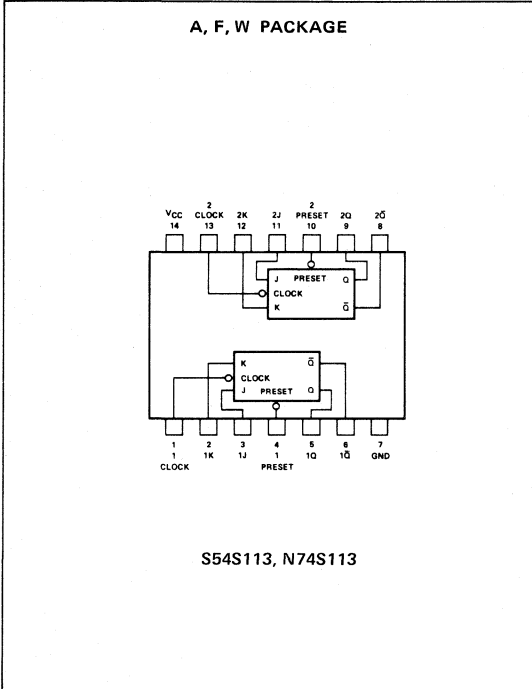
### NOTES:

- Setup time is the interval immediately preceding the negative-going edge of the clock pulse during which interval the data to be recognized must be maintained at the input to ensure its recognition.
- Hold time is the interval immediately following the negative-going edge of the clock pulse during which interval the data to be recognized must be maintained at the input to ensure its continued recognition.
- $I_{CC}$  is measured with outputs open, clock grounded, and J-K preset and clear at 4.5V.
- Load circuit and waveforms are shown on page 2-293

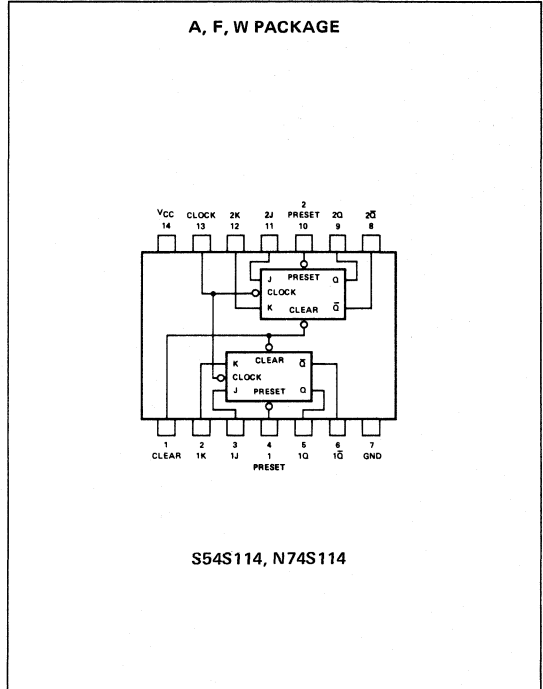
S54S113-A,F,W • S54S114-A,F,W • N74S113-A,F • N74S114-A,F

DIGITAL 54/74 TTL SERIES

#### PIN CONFIGURATIONS



#### PIN CONFIGURATIONS



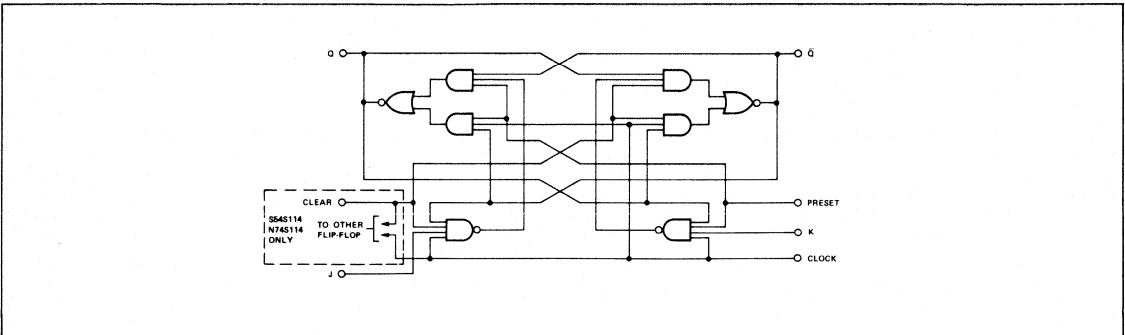
The S54S113 and N74S113 offer individual J, K, preset, and clock inputs. The S54S114 and N74S114 offer common clock and common clear inputs and individual J, K, and preset inputs.

These monolithic dual flip-flops are designed so that when the clock goes high, the inputs are enabled and data will be accepted. The logic level of the J and K inputs may be allowed to change when the clock pulse is high and the bistable will perform according to the truth table as long as minimum setup times are observed. Input data are transferred to the outputs on the negative-going edge of the clock pulse.

	$t_n$	$t_{n+1}$
J	K	$\bar{Q}$
L	L	$O_n$
L	H	L
H	L	H
H	H	$\bar{O}_n$

NOTES:  
 A.  $t_n$  = bit time before clock pulse  
 B.  $t_{n+1}$  = bit time after clock pulse

#### LOGIC DIAGRAM (each flip-flop)



# SIGNETICS DUAL J-K EDGE-TRIGGERED FLIP-FLOPS ■ S54S113, S54S114, N74S113, N74S114

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S113, S54S114			N74S113, N74S114			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N:	High logic level						
	Low logic level						
Input Clock Frequency, $f_{clock}$	0		80	0		80	MHz
Width of Clock Pulse, $t_w(\text{clock})$	6			6			ns
Width of Preset Pulse, $t_w(\text{preset})$	8			8			ns
Width of Clear Pulse, $t_w(\text{clear})$ : S54S114, N74S114	8			8			ns
Input Setup Time, $t_{setup}$	3			3			ns
Input Hold Time, $t_{hold}$	0			0			ns
Operating-Free-Air Temperature, $T_A$	-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54S113 N74S113			S54S114 N74S114			UNIT
		MIN	TYP**	MAX	MIN	TYP**	MAX	
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage	0.8			0.8			V
$V_I$	Input clamp voltage	-1.2			-1.2			V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_I = -18\text{mA}$						V
		$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}$ , Series 54S		2.5	3.4	2.5	3.4	
$V_{OL}$	Low-level output voltage	$V_{IL} = 0.8\text{V}, I_{OH} = -1\text{mA}$						V
		$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 20\text{mA}$ , Series 74S		2.7	3.4	2.7	3.4	
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1			mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$						$\mu\text{A}$
		J or K input		50		50		
		Clock		100		200		
		Preset		100		100		
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$						mA
		J or K input		-1.6		-1.6		
		Clock		-4		-8		
		Preset		-7		-7		
$I_{OS}$	Short circuit output current†	$V_{CC} = \text{MAX}$			-40			mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ , See Note 1			30			mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		$f_{max}$	Maximum clock frequency	80	
$t_{PLH}$	Propagation delay time, low-to-high-level output, from clear or preset	2	4	7	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output, from clear or preset	$C_L = 15\text{pF}, R_L = 280\Omega$	NOTE 2	7	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output, from clock	2	4	7	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output, from clock	2	5	7	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. See Figures 64 through 69 of the Series 54H/74H section for test circuits.

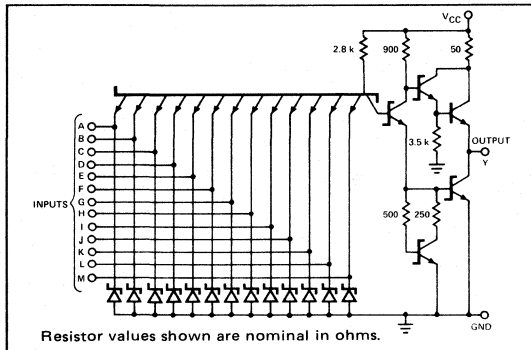
\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

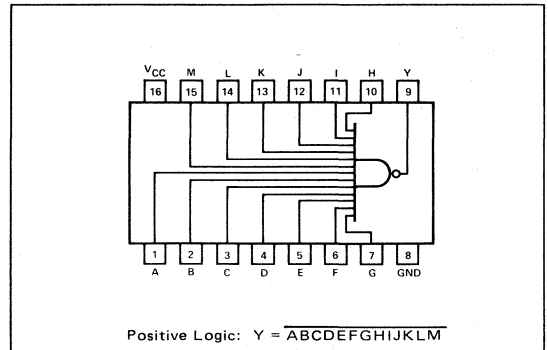
NOTE 1:  $I_{CC}$  is measured with outputs open, clock grounded, and J, K, preset, and clear at 4.5V.

2. Load circuit and waveforms are shown on page 2-293

#### SCHEMATIC



#### PIN CONFIGURATION



#### RECOMMENDED OPERATING CONDITIONS

	S54S133			N74S133			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20	20			
	Low logic level		10	10			
Operating free-air temperature, $T_A$	-55		125	0		70	$^{\circ}\text{C}$

#### ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.2	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$	S54S133	2.5	3.4	V
		N74S133	2.7	3.4	V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 20 \text{ mA}$			0.5	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1	mA
$I_{IH}$ High-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$			50	$\mu\text{A}$
$I_{IL}$ Low-level input current (each input)	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$			-2	mA
$I_{OS}$ Short-circuit output current ‡	$V_{CC} = \text{MAX}$	-40		-100	mA
$I_{CCH}$ Supply current, high-level output	$V_{CC} = \text{MAX},$ All inputs at 0 V		3	5	mA
$I_{CCL}$ Supply current, low-level output	$V_{CC} = \text{MAX},$ All inputs at 5 V		5.5	10	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ .

‡The duration of the short-circuit test should not exceed one second.

#### SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$ Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2	4	6	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$		5.5		
$t_{PHL}$ Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2	4.5	7	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$		6.5		

See Note 1

NOTE 1: Load circuit and waveforms are shown on page 2-293

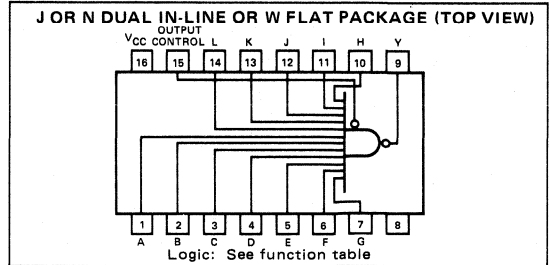


#### FUNCTION TABLE

INPUTS												OUTPUT CONTROL	OUTPUT Y
A	B	C	D	E	F	G	H	I	J	K	L		
H	H	H	H	H	H	H	H	H	H	H	H	L	L
ANY NUMBER OF INPUTS LOW												L	H
X	X	X	X	X	X	X	X	X	X	X	X	H	Z

H = high logic level, L = low logic level, X = irrelevant  
Z = high-impedance (output off)

#### PIN CONFIGURATION



#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S134			N74S134			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		40	130			
	Low logic level		10	10			
Operating free-air temperature, $T_A$	-55		125	0		70	$^{\circ}\text{C}$

#### ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54S134		N74S134		UNIT	
		MIN	TYP** MAX	MIN	TYP** MAX		
$V_{IH}$ High-level input voltage		2		2		V	
$V_{IL}$ Low-level input voltage			0.8		0.8	V	
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$		-1.2		-1.2	V	
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -2 \text{ mA}$	2.4	3.4			V	
	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -6.5 \text{ mA}$			2.4	3.2		
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 20 \text{ mA}$		0.5		0.5	V	
$I_{O(\text{off})}$ Off-state (high-impedance-state) output current	$V_{CC} = \text{MAX}, V_O = 2.4 \text{ V}$		50		50	$\mu\text{A}$	
	$V_{CC} = \text{MAX}, V_O = 0.5 \text{ V}$		-50		-50		
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$		1		1	mA	
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$		50		50	$\mu\text{A}$	
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$		-2		-2	mA	
$I_{OS}$ Short-circuit output current ‡	$V_{CC} = \text{MAX}$	-40	-100	-40	-100	mA	
$I_{CC}$ Supply current	Output high	$V_{CC} = \text{MAX}$	All inputs at 0 V	7	13	7	13
	Output low		Output control at 0 V, Other inputs at 5 V	9	16	9	16
	Output off		All inputs at 5 V	14	25	14	25

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$ .

‡Duration of the short-circuit test should not exceed one second.

#### SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		$t_{PLH}$ Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2	
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$	5.5			
$t_{PHL}$ Propagation delay time, high-to-low-level output	$C_L = 15 \text{ pF}, R_L = 280 \Omega$	2	5	7.5	ns
	$C_L = 50 \text{ pF}, R_L = 280 \Omega$	7			
$t_{ZH}$ Output enable time to high level	$C_L = 50 \text{ pF}, R_L = 280 \Omega$	13	19.5		ns
$t_{ZL}$ Output enable time to low level		14	21		ns
$t_{HZ}$ Output disable time from high level	$C_L = 5 \text{ pF}$	5.5	8.5		ns
$t_{LZ}$ Output disable time from low level		9	14		ns

NOTE 1: Load circuit and waveforms are shown on page 2-293

### DESCRIPTION

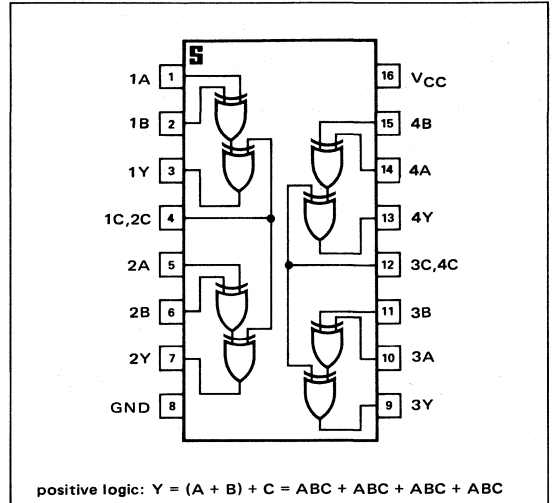
The 54/74S135 can operate as Exclusive OR Gate (C Input Low) or as Exclusive NOR Gate (C Input High). It is fully compatible with most TTL SSI & MSI circuits. Typical delay times are 8 ns.

### FUNCTION TABLE

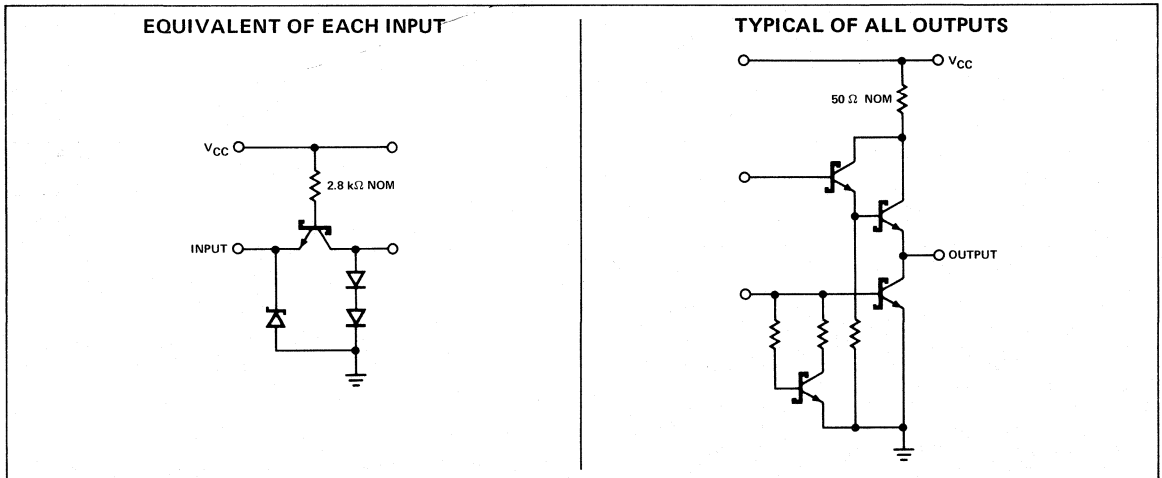
INPUTS			OUTPUT Y
A	B	C	
L	L	L	L
L	H	L	H
H	L	L	H
H	H	L	L
L	L	H	H
L	H	H	L
H	L	H	L
H	H	H	H

H = high level, L = low level

### PIN CONFIGURATION



### SCHEMATICS OF INPUTS AND OUTPUTS



### ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

Supply voltage,  $V_{CC}$  (see Note 1)

7V

Input voltage

5.5V

Operating free-air temperature range:

54S135

-55°C to 125°C

74S135

0°C to 70°C

Storage temperature range

-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

RECOMMENDED OPERATING CONDITIONS

	54S135			74S135			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
High-level output current, $I_{OH}$			-1			-1	mA
Low-level output current, $I_{OL}$			20			20	mA
Operating free-air temperature, $T_A$	-55		125	0		70	°C

ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$	54S'	2.5	3.4	V
			74S'	2.7	3.4	
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 20 \text{ mA}$			0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$			50	μA
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$			-2	mA
$I_{OS}$	Short-circuit output current‡	$V_{CC} = \text{MAX}$	-40		-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, \text{ See Note 2}$		65	99	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

‡ All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

§ Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 2:  $I_{CC}$  is measured with the inputs grounded and the outputs open.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$

PARAMETER¶	FROM (INPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$ $t_{PHL}$	A or B	B or A = L, C = L		8.5	13	ns
				11	15	
$t_{PLH}$ $t_{PHL}$	A or B	B or A = H, C = L		8	12	ns
				9	13.5	
$t_{PLH}$ $t_{PHL}$	A or B	B or A = L, C = H	$C_L = 15 \text{ pF}, R_L = 280 \Omega, \text{ See Note 3}$	10	15	ns
				6.5	10	
$t_{PLH}$ $t_{PHL}$	A or B	B or A = H, C = H		8.5	12	ns
				7	11	
$t_{PLH}$ $t_{PHL}$	C	A = B		8	12	ns
				9.5	14.5	
$t_{PLH}$ $t_{PHL}$	C	A ≠ B		7.5	11.5	ns
				8	12	

¶  $t_{PLH}$  ≡ propagation delay time, low-to-high-level output

$t_{PHL}$  ≡ propagation delay time, high-to-low-level output

NOTE 3: Load circuit and voltage waveforms are shown on page 148.

### DIGITAL 54/74 TTL SERIES

#### DESCRIPTION

These Schottky-clamped TTL MSI circuits are designed to be used in high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems these decoders can be used to minimize the effects of system decoding. When employed with high-speed memories utilizing a fast-enable circuit the delay times of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the Schottky-clamped system decoder is negligible.

The 54S138 and 74S138 decode one-of-eight lines dependent on the conditions at the three binary select inputs and the three enable inputs. Two active-low and one active-high enable inputs reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications. Typical delay time through the three-level address circuitry is 8 nanoseconds total or an average of 2.6 nanoseconds per gate level. Average power dissipation is typically 245 milliwatts or approximately 16 milliwatts each for the 15 equivalent gates.

The 54S139 and 74S139 comprise two individual two-line-to-four-line decoders in a single package. The active-low enable input can be used as a data line in demultiplexing applications. Typical total delay time is 7.5 nanoseconds through the three-gate-level address circuitry and power consumption is typically 300 milliwatts total.

All of these decoders/demultiplexers feature fully buffered inputs each of which represents only one normalized Series 54S/74S load to its driving circuit. All inputs are clamped with high-performance Schottky diodes to suppress line-ringing and simplify system design. The 54S138 and 54S139 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the 74S138 and 74S139 are characterized for  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$  industrial systems.

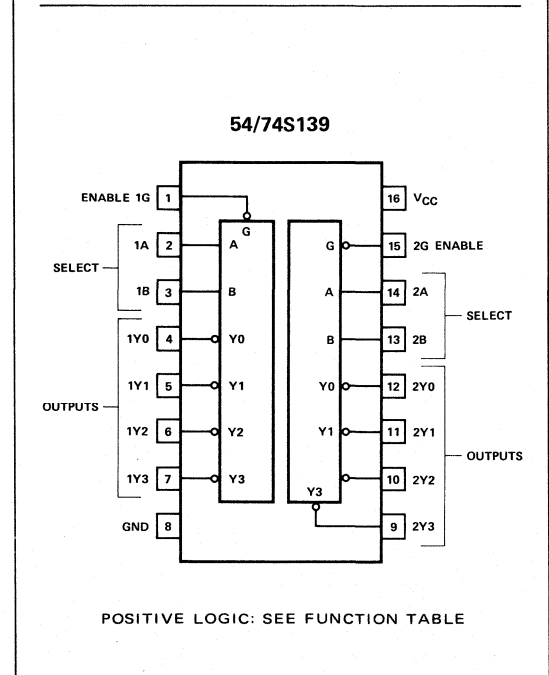
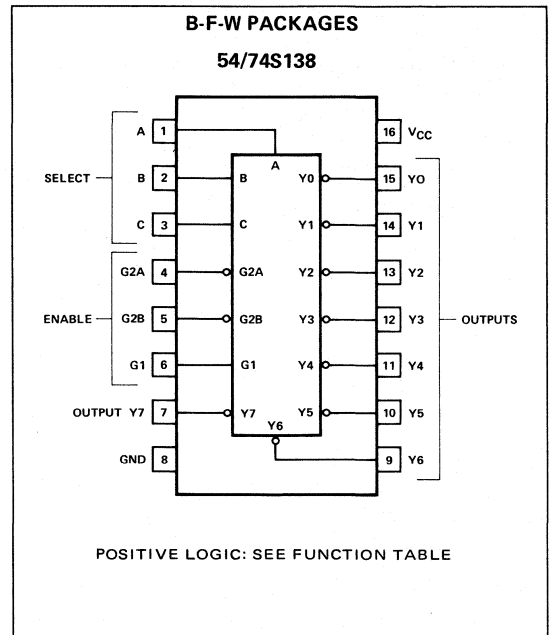
#### ABSOLUTE MAXIMUM RATING

Supply Voltage, $V_{CC}$ (See Note 1)	7 V
Input Voltage	5.5 V
Operating Free-Air Temperature Range:	
54S138, 54S139 Circuits	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
74S138, 74S139 Circuits	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $150^{\circ}\text{C}$

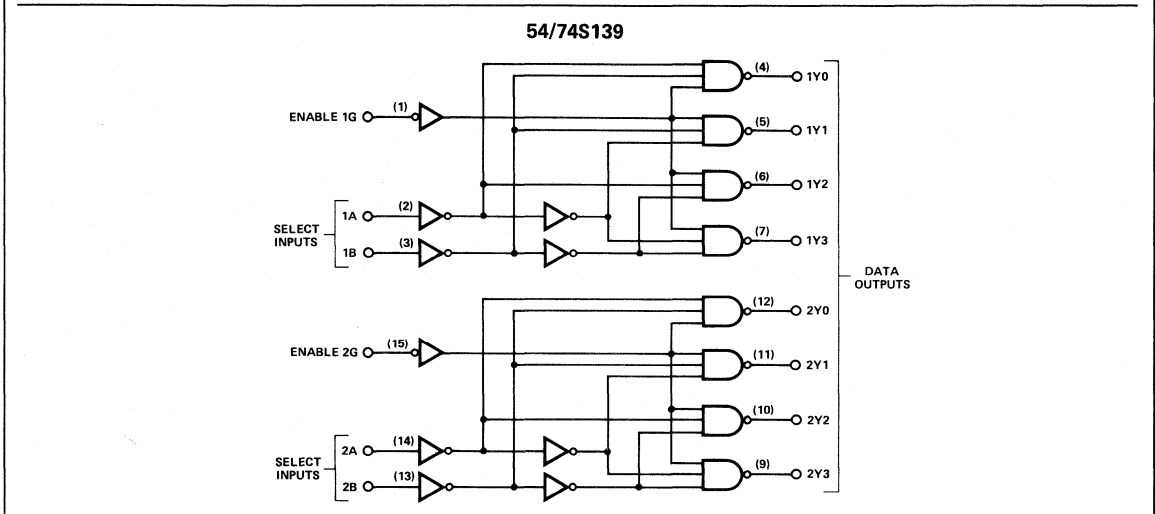
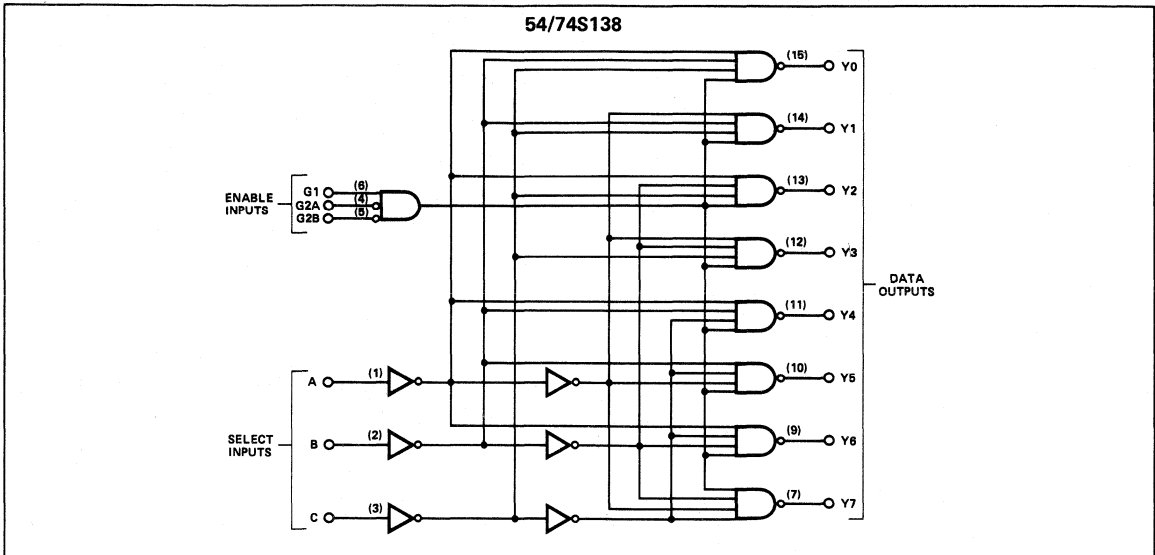
#### NOTE:

1. All voltage values are with respect to the network ground terminal.

#### PIN CONFIGURATIONS (Top View)



BLOCK DIAGRAMS



**54/74S138**  
FUNCTION TABLE

INPUTS					OUTPUTS							
ENABLE		SELECT			Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
G1	G2 <sup>1</sup>	C	B	A								
X	H	X	X	X	H	H	H	H	H	H	H	H
L	X	X	X	X	H	H	H	H	H	H	H	H
H	L	L	L	L	L	H	H	H	H	H	H	H
H	L	L	L	H	L	H	H	H	H	H	H	H
H	L	L	H	L	H	H	L	H	H	H	H	H
H	L	L	H	H	H	H	L	H	H	H	H	H
H	L	H	L	L	H	H	H	L	H	H	H	H
H	L	H	L	H	H	H	H	H	L	H	H	H
H	L	H	H	L	H	H	H	H	H	L	H	H
H	L	H	H	H	H	H	H	H	H	H	L	H

**54/74S139 FUNCTION TABLE**  
(EACH DECODER/DEMULTIPLEXER)

INPUTS			OUTPUTS			
ENABLE	SELECT		Y0	Y1	Y2	Y3
G	B	A				
H	X	X	H	H	H	H
L	L	L	L	H	H	H
L	L	H	H	L	H	H
L	H	L	H	H	L	H
L	H	H	H	H	H	L

H = High level, L = Low level, X = Irrelevant

<sup>1</sup>G2 = G2A + G2B

H = High level, L = Low level, X = Irrelevant

RECOMMENDED OPERATING CONDITIONS

PARAMETER	54S138 54S139			74S138 74S139			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output N	High logic level		20			20	
	Low logic level		10			10	
Operating free-air temperature, T <sub>A</sub>	-55		125	0		70	°C

ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range. Unless otherwise noted.)

PARAMETER	TEST CONDITIONS <sup>1</sup>	54S138 54S139			74S138 74S139			UNIT
		MIN	TYP <sup>2</sup>	MAX	MIN	TYP <sup>2</sup>	MAX	
V <sub>IH</sub> High-level input voltage		2			2			V
V <sub>IL</sub> Low-level input voltage				0.8			0.8	V
V <sub>I</sub> Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -18mA			-1.2			-1.2	V
V <sub>IH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OH</sub> = -1mA	Series 54S	2.5	3.4		2.5	3.4	V
		Series 74S	2.7	3.4		2.7	3.4	
V <sub>IL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2V, V <sub>IL</sub> = 0.8V, I <sub>OL</sub> = 20mA			0.5			0.5	V
I <sub>I</sub> Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5V			1			1	mA
I <sub>IH</sub> High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V			50			50	μA
I <sub>IL</sub> Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5V			-2			-2	mA
I <sub>OS</sub> Short-circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX	-40		-100	-40		-100	mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX, Outputs enabled and open		49	74		60	90	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.
- Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

SWITCHING CHARACTERISTICS V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C, N = 10

PARAMETER <sup>1</sup>	FROM (INPUT)	TO (OUTPUT)	LEVELS OF DELAY	TEST CONDITIONS	54S138, 74S138			54S139 74S139			UNIT
					MIN	TYP	MAX	MIN	TYP	MAX	
t <sub>PLH</sub>	Binary select	Any	2	C <sub>L</sub> = 15pF, R <sub>L</sub> = 280 Ω		4.5	7		5	7.5	ns
t <sub>PHL</sub>						7	10.5		6.5	10	
t <sub>PLH</sub>			3			7.5	12		7	12	ns
t <sub>PHL</sub>						8	12		8	12	
t <sub>PLH</sub>	Enable	Any	2			5	8		5	8	ns
t <sub>PHL</sub>						7	11		6.5	10	
t <sub>PLH</sub>			3			7	11				ns
t <sub>PHL</sub>						7	11				

NOTE:

- t<sub>PLH</sub> ≡ propagation delay time, low-to-high-level output  
t<sub>PHL</sub> ≡ propagation delay time, high-to-low-level output

#### DESCRIPTION

The S54S151, S54S251, N74S151, and N74S251 Schottky-clamped, high-performance, eight-input data selectors/multiplexers are designed for use in very high-speed data routing applications. These multiplexers select one of eight data sources when so directed by the binary address inputs. Both true and complementary data are presented when the strobe input goes low.

The S54S151 and N74S151 are functionally and mechanically interchangeable with the S54151 and N74151 respectively, and in most TTL systems can be utilized to upgrade the performance of existing designs as delay times are typically half that of the S54151 or N74151.

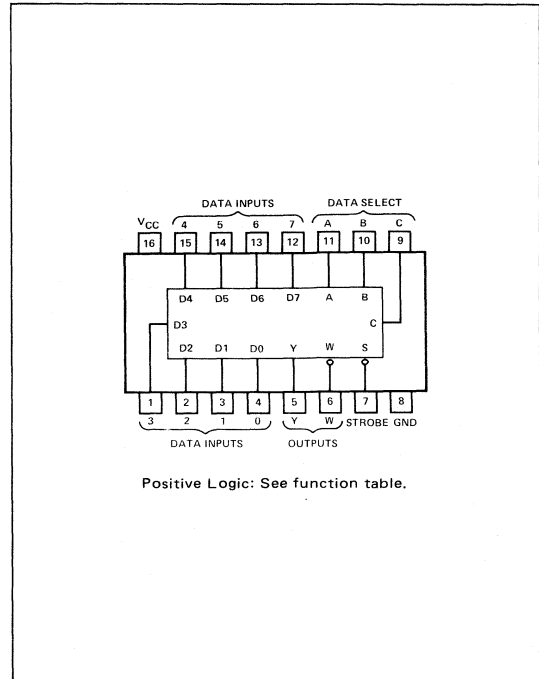
The S54S251 and N74S251 have three-state outputs which permit the outputs to be connected to a common bus. When the strobe input is high, both outputs are in a high-impedance state in which both the upper and lower transistors of each totem-pole output are off, and the output can neither drive nor load the bus. When the strobe is low, the outputs are activated and operate as standard TTL totem-pole outputs.

Typical power dissipation is 225 milliwatts for the S54S151 or N74S151 and 275 milliwatts for the S54S251 and N74S251, or approximately 14 and 17 milliwatts respectively per equivalent gate. The S54S151 and S54S251 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74S151 and N74S251 are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S151			S54S251			N74S151			N74S251			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.5	5	5.5	4.75	5	5.25	4.75	5	5.25	V
Normalized fan-out from each output, N (at a low logic level)	10			10			10			10			
High-level output current, $I_{OH}$	-1			-2			-1			-6.5			mA
Operating free-air temperature, $T_A$	-55		125	-55		125	0	70		0	70		$^{\circ}\text{C}$

#### PIN CONFIGURATION



#### FEATURES

- S54S151/N74S151 INTERCHANGEABLE WITH S54151/N74151 IN MOST SYSTEMS
- SCHOTTKY CLAMPED FOR SIGNIFICANT REDUCTION IN DELAY TIMES... 4.5 ns TYPICAL, DATA INPUT TO W OUTPUT
- HIGH-SPEED SELECTION FOR ONE OF EIGHT DATA SOURCES
- PERMITS MULTIPLEXING FROM N LINES TO ONE LINE
- S54S251 AND N74S251 HAVE TRI-STATE OUTPUTS
- FULLY COMPATIBLE WITH SERIES 54/74 AND OTHER TTL MSI CIRCUITS

# SIGNETICS 8-INPUT DATA SELECTORS/MULTIPLEXERS ■ S54/N74S151, S54/N74S251

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54S151 N74S151		S54S251 N74S251		UNIT
		MIN	TYP** MAX	MIN	TYP** MAX	
V <sub>IH</sub> High-level input voltage		2		2		V
V <sub>IL</sub> Low-level input voltage			0.8		0.8	V
V <sub>I</sub> Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA		-1.2		-1.2	V
V <sub>OH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = MAX	Series 54S 2.5	3.4	Series 54S 2.4	3.2	V
		Series 74S 2.7	3.4	Series 74S 2.4	3.2	
V <sub>OL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 20 mA		0.5		0.5	V
I <sub>O(off)</sub> Off-state (high-impedance-state) output current	V <sub>CC</sub> = MAX, V <sub>O</sub> = 2.7 V				50	μA
	V <sub>CC</sub> = MAX, V <sub>O</sub> = 0.4 V				-50	
I <sub>I</sub> Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V		1		1	mA
I <sub>IH</sub> High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7 V		50		50	μA
I <sub>IL</sub> Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5 V		-2		-2	mA
I <sub>OS</sub> Short-circuit output current ‡	V <sub>CC</sub> = MAX	-40	-100	-40	-100	mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX, All inputs at 4.5 V, All outputs open	45	70	55	85	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C.

‡Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

## SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	S54S151, N74S151			S54S251, N74S251			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
t <sub>PLH</sub>	A, B, or C (4 levels)	Y	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 280 Ω, See Note 1		12	18		12	18	ns
t <sub>PHL</sub>					12	18		13	19.5	
t <sub>PLH</sub>	A, B, or C (3 levels)	W			10	15		10	15	ns
t <sub>PHL</sub>					9	13.5		9	13.5	
t <sub>PLH</sub>	Any D	Y			8	12		8	12	ns
t <sub>PHL</sub>					8	12		8	12	
t <sub>PLH</sub>	Any D	W			4.5	7		4.5	7	ns
t <sub>PHL</sub>					4.5	7		4.5	7	
t <sub>PLH</sub>	Strobe	Y			11	16.5				ns
t <sub>PHL</sub>					12	18				
t <sub>PLH</sub>	Strobe	W			9	13				ns
t <sub>PHL</sub>					8.5	12				
t <sub>ZH</sub>	Strobe	Y	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 280 Ω, See Note 1				13	19.5	ns	
t <sub>ZL</sub>							14	21		
t <sub>ZH</sub>	Strobe	W					13	19.5	ns	
t <sub>ZL</sub>							14	21		
t <sub>HZ</sub>	Strobe	Y		C <sub>L</sub> = 5 pF, R <sub>L</sub> = 280 Ω, See Note 1				5.5	8.5	ns
t <sub>LZ</sub>								9	14	
t <sub>HZ</sub>	Strobe	W					5.5	8.5	ns	
t <sub>LZ</sub>							9	14		

t<sub>PLH</sub> ≡ Propagation delay time, low-to-high-level output

t<sub>PHL</sub> ≡ Propagation delay time, high-to-low-level output

t<sub>ZH</sub> ≡ Output enable time to high level

t<sub>ZL</sub> ≡ Output enable time to low level

t<sub>HZ</sub> ≡ Output disable time from high level

t<sub>LZ</sub> ≡ Output disable time from low level

NOTE 1: See load circuits and waveforms on page 2-293



**SIGNETICS 8-INPUT DATA SELECTORS/MULTIPLEXERS ■ S54/N74S151, S54/N74S251**

FUNCTION TABLE

SELECT				INPUTS								OUTPUTS							
C B A			STROBE	DATA								S54S151,		N74S151		S54S251,		N74S251	
C	B	A	S	D0	D1	D2	D3	D4	D5	D6	D7	Y	W	Y	W				
X	X	X	H	X	X	X	X	X	X	X	X	L	H	Z	Z				
L	L	L	L	L	X	X	X	X	X	X	X	L	H	L	H				
L	L	L	L	L	H	X	X	X	X	X	X	H	L	H	L				
L	L	H	L	L	X	L	X	X	X	X	X	L	H	L	H				
L	L	H	L	L	X	H	X	X	X	X	X	H	L	H	L				
L	H	L	L	L	X	X	L	X	X	X	X	L	H	L	H				
L	H	L	L	L	X	X	H	X	X	X	X	H	L	H	L				
L	H	H	L	L	X	X	X	L	X	X	X	L	H	L	H				
L	H	H	L	L	X	X	X	H	X	X	X	H	L	H	L				
H	L	L	L	L	X	X	X	X	L	X	X	L	H	L	H				
H	L	L	L	L	X	X	X	X	H	X	X	H	L	H	L				
H	L	H	L	L	X	X	X	X	X	L	X	L	H	L	H				
H	L	H	L	L	X	X	X	X	X	H	X	H	L	H	L				
H	H	L	L	L	X	X	X	X	X	L	X	L	H	L	H				
H	H	L	L	L	X	X	X	X	X	H	X	H	L	H	L				
H	H	H	L	L	X	X	X	X	X	X	L	L	H	L	H				
H	H	H	L	L	X	X	X	X	X	X	H	H	L	H	L				

H = high logic level, L = low logic level, Z = high impedance, X = irrelevant

#### DESCRIPTION

These monolithic Schottky-barrier-diode-clamped TTL circuits are high-performance multiplexers which are significantly faster than the S54153/N74153. As an example, the two-gate-level delay from the data inputs to the output is only 8.5 nanoseconds maximum compared to 18 or 23 nanoseconds maximum for the standard-speed part. Overall, the guaranteed delay times for the S54S153/N74S153 represent approximately a 100% improvement over standard TTL with only a 12% increase in maximum d-c power consumption. In many cases, the S54S153 or N74S153 can plug into existing systems designed for S54153 or N74153.

These data selectors/multiplexers are fully compatible for use with most standard, high-speed, and low-power TTL and DTL circuits. Each diode-clamped input represents only one normalized Series 54S/74S load, and full fan-out to 10 normalized Series 54S/74S loads is available from each of the outputs at low logic levels. A fan-out to 20 normalized Series 54S/74S loads is provided at high logic levels to facilitate connection of unused inputs to used inputs. Typical power dissipation is 225 milliwatts.

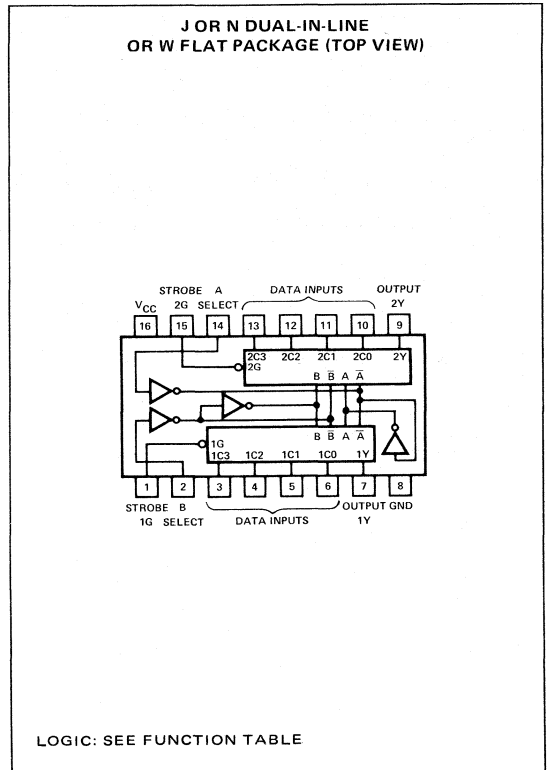
The S54S153 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74S153 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### FEATURES

- FULL SCHOTTKY-BARRIER-DIODE CLAMPING FOR VERY HIGH SPEEDS
- PERMITS MULTIPLEXING FROM N LINES TO 1 LINE
- SAME PIN ASSIGNMENTS AS S54153 AND N74153
- STROBE (ENABLE) LINE PROVIDED FOR CASCADING (N LINES TO n LINES)
- TYPICAL AVERAGE PROPAGATION DELAY TIMES:
 

DATA INPUT TO OUTPUT (2 GATE LEVELS)	6 ns
STROBE INPUT TO OUTPUT (3 GATE LEVELS)	9.5 ns
SELECT INPUT TO OUTPUT (4 GATE LEVELS)	12 ns
- HIGH FAN-OUT LOW-IMPEDANCE TOTEM-POLE OUTPUTS
- FULLY COMPATIBLE WITH MOST TTL AND DTL CIRCUITS

#### PIN CONFIGURATION



#### FUNCTION TABLE

SELECT INPUTS		DATA INPUTS				STROBE	OUTPUT
B	A	C0	C1	C2	C3	G	Y
X	X	X	X	X	X	H	L
L	L	L	X	X	X	L	L
L	L	H	X	X	X	L	H
L	H	X	L	X	X	L	L
L	H	X	H	X	X	L	H
H	L	X	X	L	X	L	L
H	L	X	X	H	X	L	H
H	H	X	X	X	L	L	L
H	H	X	X	X	H	L	H

Address inputs A and B are common to both sections.  
H = High level, L = Low level, X = Irrelevant

# SIGNETICS DUAL 4-LINE TO 1-LINE DATA SELECTORS/MULTIPLEXERS ■ S54S153, N74S153

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		S54S153			N74S153			UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX			
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V		
Normalized fan-out from each output, N	High logic level	20			20					
	Low logic level	10			10					
Operating free-air temperature range, $T_A$		-55			125			0	70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input clamp Voltage	$V_{CC} = \text{MIN}$ ,	$I_I = -18 \text{ mA}$			-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IL} = 0.8 \text{ V}$ ,	$V_{IH} = 2 \text{ V}$ ,	Series 54S	2.5	3.4	V
			$I_{OH} = -1 \text{ mA}$	Series 74S	2.7	3.4	
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IL} = 0.8 \text{ V}$ ,	$V_{IH} = 2 \text{ V}$ , $I_{OL} = 20 \text{ mA}$			0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}$ , $V_I = 5.5 \text{ V}$				1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}$ , $V_I = 2.7 \text{ V}$				50	$\mu\text{A}$
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}$ , $V_I = 0.5 \text{ V}$				-2	mA
$I_{OS}$	Short-circuit output current:‡	$V_{CC} = \text{MAX}$		-40		-100	mA
$I_{CCL}$	Supply current, low level output	$V_{CC} = \text{MAX}$ , See Note 1			45	70	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

‡Not more than one output should be shorted at a time.

NOTE: 1:  $I_{CCL}$  is measured with the outputs open and all inputs grounded.

## SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}$ , $T_A = 25^\circ\text{C}$ , N = 10

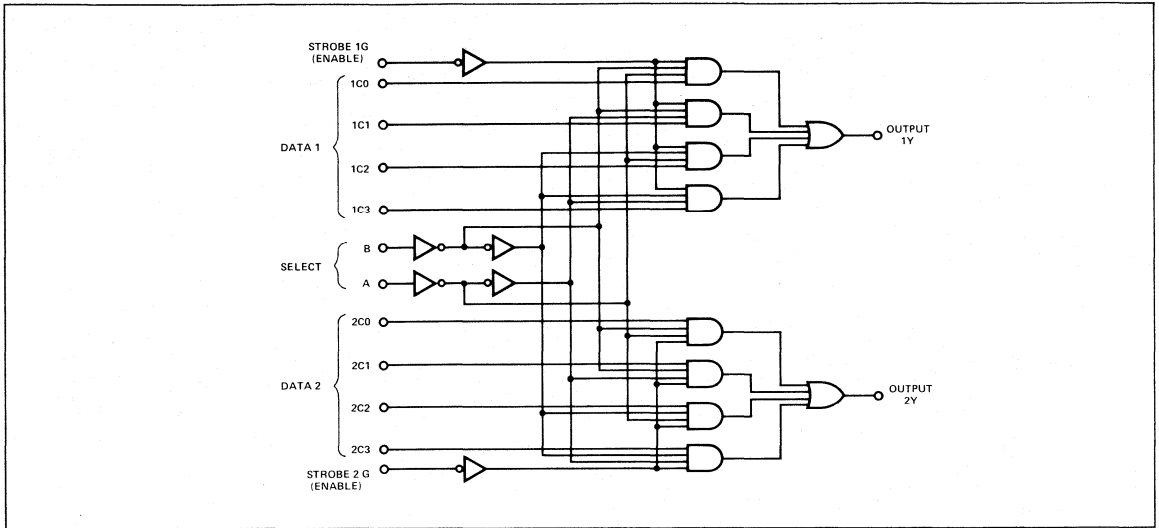
PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Data	Y	$C_L = 15 \text{ pF}$ , $R_L = 280 \Omega$ , See Note 2		6	9	ns
$t_{PHL}$	Data	Y			6	9	ns
$t_{PLH}$	Select	Y			11.5	18	ns
$t_{PHL}$	Select	Y			12	18	ns
$t_{PLH}$	Strobe	Y			10	15	ns
$t_{PHL}$	Strobe	Y			9	13.5	ns

$t_{PLH}$  ≡ Propagation delay time, low-to-high-level output.

$t_{PHL}$  ≡ Propagation delay time, high-to-low-level output.

NOTE 2: Load circuit and test waveforms are shown on page 2-293

FUNCTIONAL BLOCK DIAGRAM



TEST TABLE FOR NOTE 2

INPUTS							OUTPUT Y WAVEFORM
B	A	C0	C1	C2	C3	G	
GND	GND	INPUT	X	X	X	GND	A
GND	4.5 V	X	INPUT	X	X	GND	A
4.5 V	GND	X	X	INPUT	X	GND	A
4.5 V	4.5 V	X	X	X	INPUT	GND	A
GND	INPUT	GND	4.5 V	X	X	GND	A
INPUT	GND	GND	X	4.5 V	X	GND	A
GND	GND	4.5 V	X	X	X	INPUT	B

X = Irrelevant    A=IN-PHASE OUTPUT  
 B=OUT-OF-PHASE

#### DESCRIPTION

The Schottky-clamped S54S157, S54S158, N74S157, and N74S158 are ultra-high-speed data selectors/multiplexers which can be employed in high-performance designs. These circuits select a 4-bit word from one of two sources and route it to the four outputs. The S54S157/N74S157 present true data whereas the S54S158/N74S158 present inverted data to minimize propagation delay time.

The S54S157/N74S157 can be used to replace the S54157/N74157 in existing designs to upgrade performance substantially.

The S54S157 and S54S158 are characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The N74S157 and N74S158 are characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### FEATURES

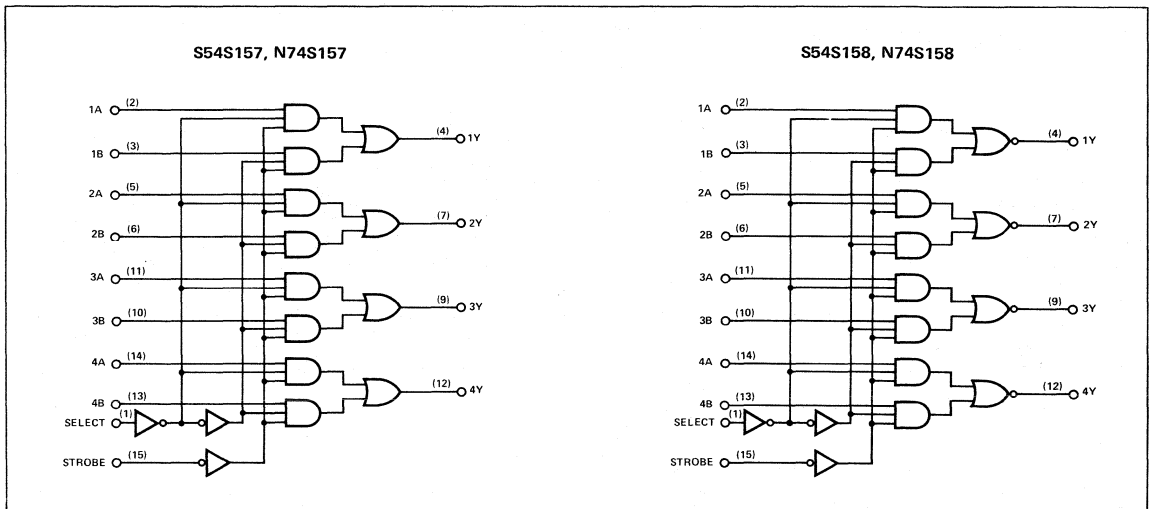
- SCHOTTKY-CLAMPING REDUCES DELAY TIME TO 4 ns TYPICAL (S54S158, N74S158 DATA-TO-OUTPUT)
- S54S157, N74S157 CAN UPGRADE EXISTING SYSTEM PERFORMANCE AS THEY ARE PIN-FOR-PIN REPLACEMENTS FOR S54157, N74157
- S54S157, S54S158 OPERATE THROUGHOUT  $-55^{\circ}\text{C}$  TO  $125^{\circ}\text{C}$  FREE-AIR TEMPERATURE RANGE
- FULLY COMPATIBLE WITH MOST TTL AND TTL MSI CIRCUITS

#### FUNCTION TABLE

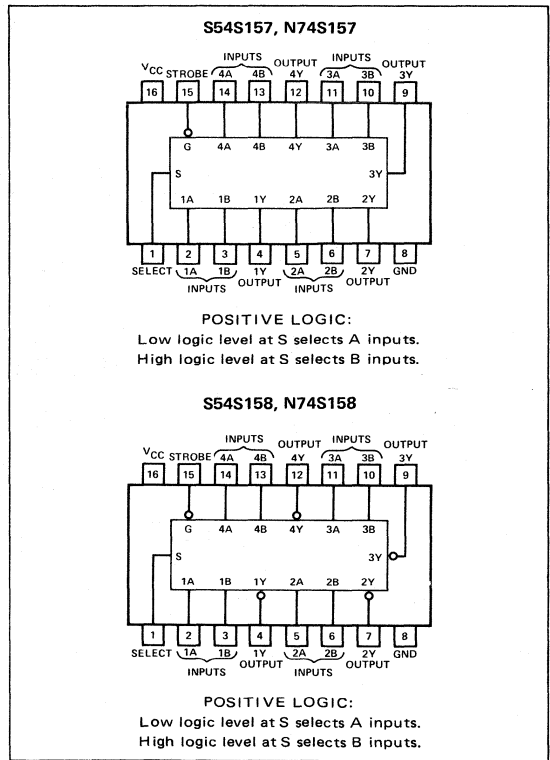
INPUTS		OUTPUT Y		
STROBE	SELECT	A B	S54S157 N74S157	S54S158 N74S158
H	X	X X	L	H
L	L	L X	L	H
L	L	H X	H	L
L	H	X L	L	H
L	H	X H	H	L

H = high level, L = low level, X = irrelevant

#### LOGIC DIAGRAM



#### PIN CONFIGURATION



# SIGNETICS QUADRUPLE 2-LINE TO 1-LINE ■ S54S157, S54S158, N74S157, N74S158

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		S54S157, S54S158			N74S157, N74S158			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level	20			20			
	Low logic level	10			10			
Operating free-air temperature, $T_A$		-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54S157 N74S157		S54S158 N74S158		UNIT	
		MIN	TYP**	MAX	MIN		TYP**
$V_{IH}$ High-level input voltage		2		2		V	
$V_{IL}$ Low-level input voltage		0.8		0.8		V	
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}$ , $I_I = -18 \text{ mA}$	-1.2		-1.2		V	
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IH} = 2 \text{ V}$ $V_{IL} = 0.8 \text{ V}$ , $I_{OH} = -1 \text{ mA}$	Series 54S	2.5	3.4	2.5	3.4	V
		Series 74S	2.7	3.4	2.7	3.4	
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IH} = 2 \text{ V}$ , $V_{IL} = 0.8 \text{ V}$ , $I_{OL} = 20 \text{ mA}$	0.5		0.5		V	
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}$ , $V_I = 5.5 \text{ V}$	1		1		mA	
$I_{IH}$ High-level input current	S or G input	100		100		$\mu\text{A}$	
	A or B input	50		50			
$I_{IL}$ Low-level input current	S or G input	-4		-4		mA	
	A or B input	-2		-2			
$I_{OS}$ Short-circuit output current‡	$V_{CC} = \text{MAX}$	-40	-100	-40	-100	mA	
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , See Note 1	50		78	39	61	mA

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

‡Not more than one output should be shorted at a time and duration of the short-circuit test should not exceed one second.

NOTE 1:  $I_{CC}$  is measured with 4.5 V applied to all inputs and all outputs open.

## SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}$ , $T_A = 25^\circ\text{C}$ , N = 10

PARAMETER	FROM (INPUT)	TEST CONDITIONS	S54S157, N74S157			S54S158, N74S158			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
$t_{PLH}$	Data	$C_L = 15 \text{ pF}$ , $R_L = 280 \Omega$ , See Note 2	5		7.5	4		6	ns
$t_{PHL}$			4.5		6.5	4		6	
$t_{PLH}$	Strobe		8.5		12.5	6.5			ns
$t_{PHL}$			7.5		12	7			
$t_{PLH}$	Select		9.5		15	8		12	ns
$t_{PHL}$			9.5		15	8		12	

$t_{PLH} \equiv$  Propagation delay time, low-to-high-level output

$t_{PHL} \equiv$  Propagation delay time, high-to-low-level output

NOTE 2: Load circuits and waveforms are shown on page 2-293

### DESCRIPTION

The 74S172, containing the equivalent of 201 gates on a monolithic chip, is a high-performance 16-bit register file organized as eight words of two bits each.

Multiple address decoding circuitry is used so that the read and write operation can be performed independently on two word locations. This provides a true simultaneous read/write capability. Basically, the file consists of two distinct sections (see Figure 1).

Section 1 permits the writing of data into any two-bit word location while reading two bits of data from another location simultaneously. To provide this flexibility, independent decoding is incorporated.

Section 2 of the register file is similar to section 1 with the exception that common read/write address circuitry is employed. This means that section 2 can be utilized in one of three modes:

- 1) Writing new data into two bits
- 2) Reading from two bits
- 3) Writing into and simultaneously reading from the same two bits.

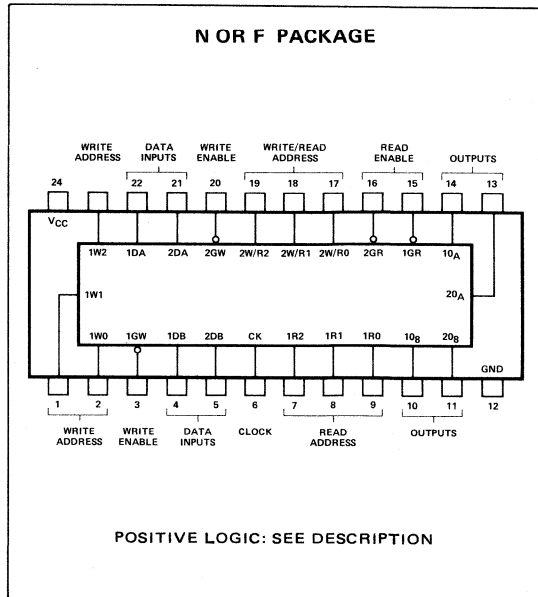
Regardless of the mode, the operation of section 2 is entirely independent of section 1.

The three-state outputs of this register file permit connection of up to 129 compatible outputs and one Series 54/74 high-logic-level load to a common system bus. The outputs are controlled by the read-enable circuitry so that they operate as standard TTL totem-pole outputs when the appropriate read-enable input is low or they are placed in a high-impedance state when the associated read-enable input is at a high logic level. To minimize the possibility that two outputs from separate register files will attempt to take a common bus to opposite logic levels, the read-enable circuitry is designed such that disable times are shorter than enable times.

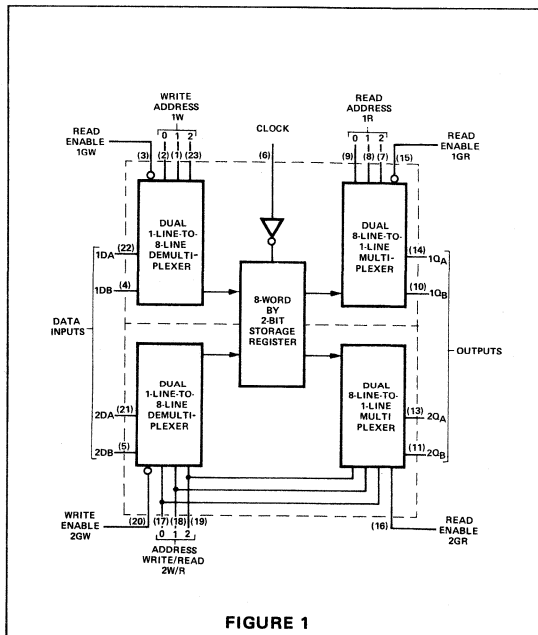
All inputs are buffered to lower the drive requirements of the clock, read/write address, and write-enable inputs to one normalized Series 54/74 load, and of all other inputs to one-half of one normalized Series 54/74 load.

Functions of the inputs and outputs of the 74S172 are as shown in the following table.

### PIN CONFIGURATION



### BLOCK DIAGRAM



## FUNCTION TABLE

FUNCTION	SECTION 1	SECTION 2	DESCRIPTION
Write Address	1W0, 1W1, 1W2	2W/R0, 2W/R1, 2W/R2	Binary write address selects one of eight two-bit word locations.
Write Enable	1GW	2GW	When low, permits the writing of new data into the selected word location on a positive transition of the clock input.
Data Inputs	1DA, 1DB	2DA, 2DB	Data at these inputs is entered on a positive transition of the clock input into the location selected by the write address inputs if the write enable input is low. Since the two sections are independent, it is possible for both write functions to be activated with both write addresses selecting the same word location. If this occurs and the information at the data inputs is not the same for both sections (i.e., 1DA≠2DA and/or 1DB≠2DB) the low-level data will predominate in each bit and be stored.
Read Address	1R0, 1R1, 1R2	Common with write address	Binary write address selects one of eight two-bit word locations.
Read Enable	1GR	2GR	When read enable is low, the outputs assume the levels of the data stored in the location selected by read address inputs. When read enable is high, the associated outputs remain in the high-impedance state and neither significantly load nor drive the lines to which they are connected.
Data Outputs	1QA, 1QB	2QA, 2QB	
Clock	CK		The positive-going transition of the clock input will enter new data into the addressed location if the write enable input is low. The clock is common to both sections.

**ABSOLUTE MAXIMUM RATINGS.** (Over Operating Free-Air Temperature Range Unless Otherwise Noted).

Supply Voltage (See Note 1)	7 V
Input Voltage	5.5 V
Output Voltage (See Note 2)	5.5 V
Operating Free-Air Temperature Range	0°C to 70°C

Storage Temperature

-65°C to 150°C

## NOTES:

1. Voltage values are with respect to network ground terminal.
2. This is the maximum voltage which should be applied to any output when it is in the high-impedance state.



## RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply voltage, $V_{CC}$		4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level			130	MHz
	Low logic level			.10	
Input clock frequency, $f_{clock}$		0		20	
Width of clock pulse, $t_w(\text{clock})$		25			ns
Setup time, $t_{setup}$ (See Figure 1)	Write select	$t_w(\text{clock})+10$			ns
	High-level data	30			
	Low-level data	30			
	Write enable	35			
Hold time, $t_{hold}$ (See Figure 1)	Write select	0			ns
	Write enable	0			
Data release time, $t_{release}$ (See Figure 1)	High-level data			10	ns
	Low-level data			10	
Operating free-air temperature, $T_A$		0		70	°C

## ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS <sup>1</sup>	MIN	TYP <sup>2</sup>	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage				-1.5	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$				V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V},$ $V_{IL} = 0.8\text{V}, I_{OH} = -5.2\text{mA}$	2.4			V
$I_{O(\text{off})}$	Off-state (high-impedance state) output current	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V},$ $V_{IL} = 0.8\text{V}, I_{OL} = 16\text{mA}$			0.4	V
		$V_{CC} = \text{MAX}, V_O = 2.4\text{V}$			40	$\mu\text{A}$
		$V_{CC} = \text{MAX}, V_O = 0.4\text{V}$			-40	$\mu\text{A}$
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			40	$\mu\text{A}$
$I_{IL}$	Low-level input current	2W/R0, 2W/R1, 2W/R2,			-1.6	mA
		1GW, 2GW, or clock	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$		-0.8	
		Any other input				
$I_{OS}$	Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX}$	-18		-55	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, \text{All inputs at } 4.5\text{V},$ Outputs open		112	170	mA

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

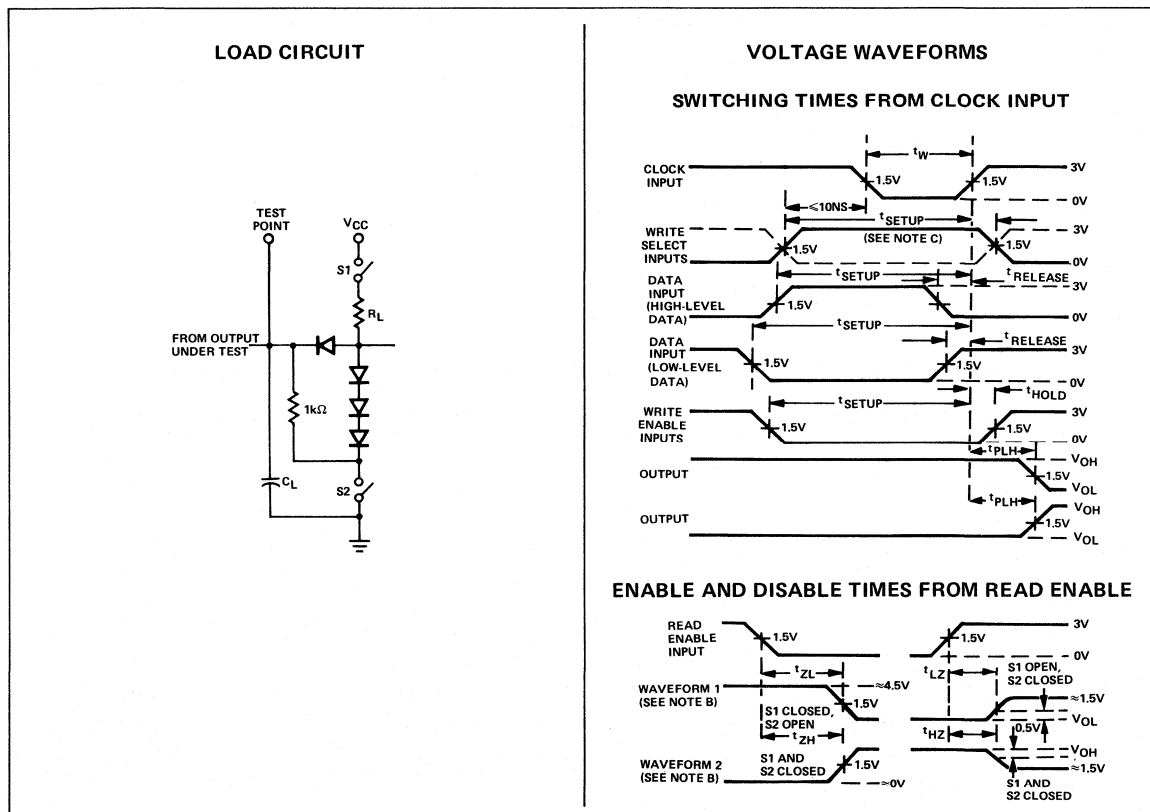
2. All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .

3. No more than one output should be shorted at a time.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum clock frequency		25		MHz
$t_{PLH}$	Propagation delay time, low-to-high-level output from read select		25	38	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output from read select	$C_L = 50pF$	20	35	ns
$t_{PLH}$	Propagation delay time, low-to-high-level output from clock	$R_L = 400\Omega$	25	38	ns
$t_{PHL}$	Propagation delay time, high-to-low-level output from clock	See Figure 1	25	38	ns
$t_{ZH}$	Output enable time to high level		10	14	ns
$t_{ZL}$	Output enable time to low level		10	16	ns
$t_{HZ}$	Output disable time from high level	$C_L = 5pF$ ,	6	20	ns
$t_{LZ}$	Output disable time from low level	See Figure 1	8	20	ns

PARAMETER MEASUREMENT INFORMATION



NOTES:

1. Input waveforms are supplied by pulse generators having the following characteristics:  $t_r \leq 7$  ns,  $t_f \leq 7$  ns, PRR = 1 MHz,  $Z_{OUT} \approx 50\Omega$ .
2. Waveform 1 is for an output with internal conditions such that the output is low except when disabled. Waveform 2 is for an output with internal conditions such that the output is high except when disabled.
3. Write select setup time, as specified, will protect data written into previous address.

### DESCRIPTION

These high-performance monolithic, positive-edge-triggered flip-flops utilize Schottky TTL technology to implement D-type flip-flop logic. All have a direct clear input, and the S54S175 and N74S175 feature complementary outputs from each flip-flop. Pin assignments for these Schottky flip-flops are identical to the standard TTL versions meaning that these Schottky versions can be utilized to upgrade existing system performance in most cases.

Information at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output.

### FEATURES

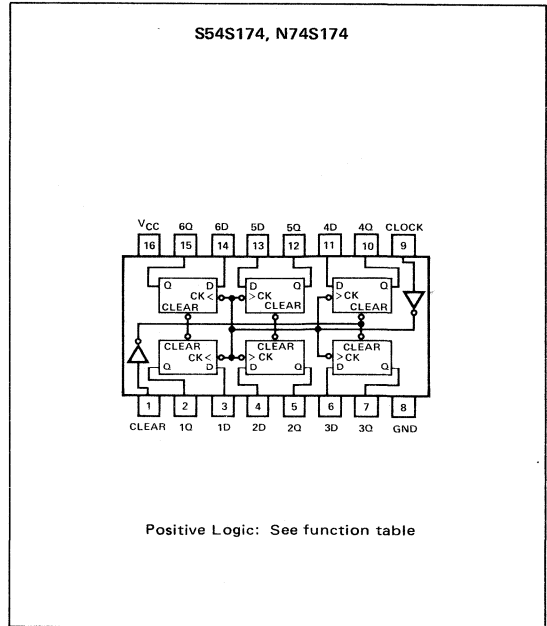
- FULL SCHOTTKY CLAMPING TO ACHIEVE TYPICAL MAXIMUM TOGGLE RATES OF 110 MHz
- FUNCTIONALLY AND MECHANICALLY IDENTICAL TO THE SERIES 54/74 COUNTERPARTS AND CAN BE USED TO UPGRADE EXISTING SYSTEMS WITH SIGNIFICANT IMPROVEMENT IN SPEED
- FULLY COMPATIBLE WITH OTHER TTL CIRCUITS
- S54S174 AND S54S175 OPERATE OVER FULL MILITARY TEMPERATURE RANGE OF  $-55^{\circ}\text{C}$  TO  $125^{\circ}\text{C}$
- FOR USE IN HIGH-PERFORMANCE:
  - BUFFER/STORAGE REGISTERS
  - SHIFT REGISTERS
  - COUNTERS
  - PATTERN GENERATORS

### FUNCTION TABLE (EACH FLIP-FLOP)

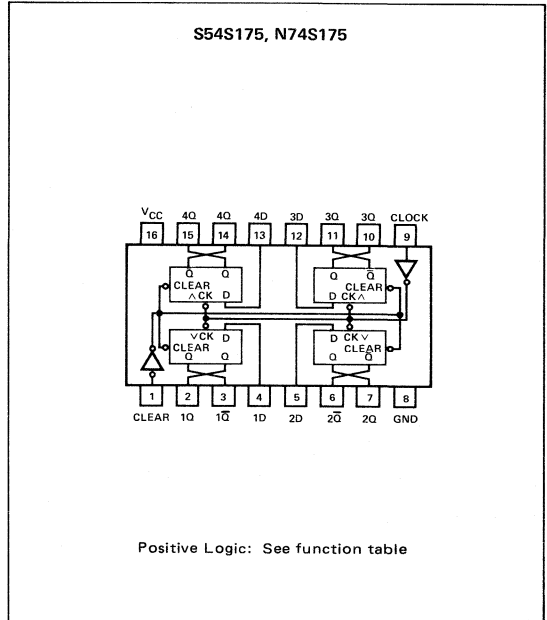
INPUTS			OUTPUTS	
CLEAR	CLOCK	D	Q	$\bar{Q}$ †
L	X	X	L	H
H	↑	H	H	L
H	↑	L	L	H
H	L	X	$Q_0$	$\bar{Q}_0$

- H = High level (steady state)
- L = Low level (steady state)
- X = Irrelevant
- ↑ = Transition from low to high level
- $Q_0$  = The level of Q before the indicated steady-state input conditions were established
- † = S54S175 and N74S175 only

### PIN CONFIGURATION



### PIN CONFIGURATION



# SIGNETICS HEX QUADRUPLE D-TYPE FLIP-FLOPS WITH CLEAR ■ S54/N74S174, S54/N74S175

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		S54S174, S54S175			N74S174, N74S175			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level	20			20			
	Low logic level	10			10			
Input clock frequency, $f_{clock}$		0	75		0	75		MHz
Width of clock or clear pulse, $t_w$		12			12			ns
Setup time, $t_{setup}$	Data input	8			8			ns
	Clear inactive-state	15			15			
Data hold time, $t_{hold}$		2			2			ns
Operating free-air temperature, $T_A$		-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage			2			V
$V_{IL}$	Low-level input voltage					0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}$ , $I_I = -18 \text{ mA}$				-1.2	V
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IH} = 2 \text{ V}$ , $V_{IL} = 0.8 \text{ V}$ , $I_{OH} = -1 \text{ mA}$	Series 54S	2.5	3.4		V
			Series 74S	2.7	3.4		
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IH} = 2 \text{ V}$ , $V_{IL} = 0.8 \text{ V}$ , $I_{OL} = 20 \text{ mA}$				0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}$ , $V_I = 5.5 \text{ V}$				1	mA
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}$ , $V_I = 2.7 \text{ V}$				50	μA
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}$ , $V_I = 0.5 \text{ V}$				-2	mA
$I_{OS}$	Short-circuit output current‡	$V_{CC} = \text{MAX}$		-40		-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}$ , See Note 1	S54S174, N74S174	90		mA	
			S54S175, N74S175	60			

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^\circ \text{C}$ .

‡Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

NOTE 1: With all outputs open and 4.5 V applied to all data and clear inputs,  $I_{CC}$  is measured after a momentary ground, then 4.5 V, is applied to clock.

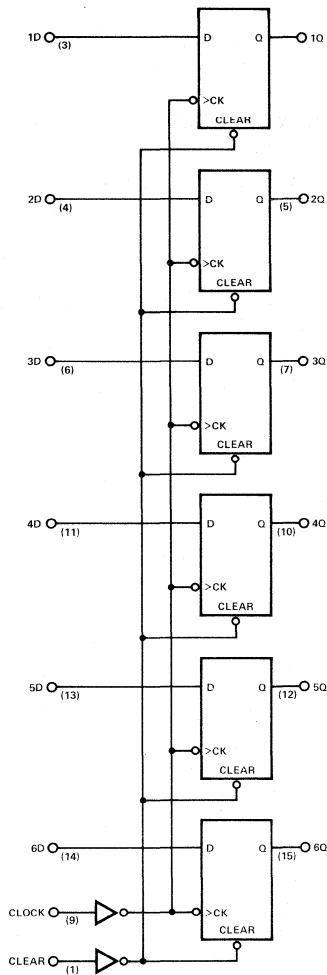
## SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}$ , $T_A = 25^\circ \text{C}$ , N = 10

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$	Maximum input clock frequency	$C_L = 15 \text{ pF}$ , $R_L = 280 \Omega$ , See Note 2	75	110		MHz
$t_{PLH}$	Propagation delay time, low-to-high-level $\bar{Q}$ output from clear (S54S175, N74S175 only)			13		ns
$t_{PHL}$	Propagation delay time, high-to-low-level Q output from clear			13		ns
$t_{PLH}$	Propagation delay time, low-to-high-level output from clock			9		ns
$t_{PHL}$	Propagation time, high-to-low-level output from clock			11		ns

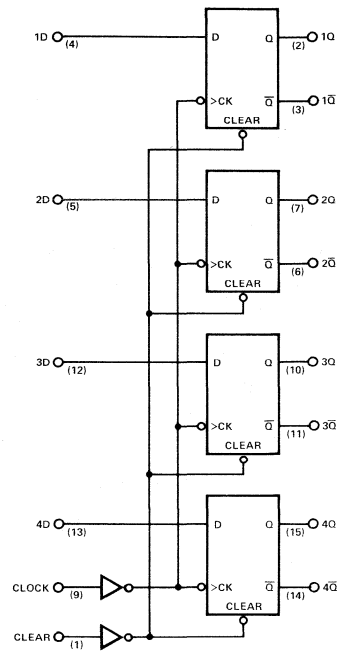
NOTE 2: See load circuit and waveforms shown on page 2-293


FUNCTIONAL BLOCK DIAGRAMS

S54S174, N74S174



S54S175, N74S175



 . . . . . Dynamic input activated by a transition from a high level to a low level.

### DESCRIPTION

The 74S178 is a 4-bit Shift Register with both serial and parallel data entry capability.

The data input lines are single-ended true input data lines which condition their specific register bit location after an enabled clocking transition. Since data transfer is synchronous with clock, data may be transferred in any serial/parallel input/output relationship.

Mode control logic is available to determine three possible control states. These register states are serial shift right mode, parallel enter mode, and no change or hold mode. These states accomplish logical decoding for system control.

The 74S179 provides a direct reset ( $R_D$ ), and a  $\overline{D}_{out}$  line in addition to the available outputs of the 82S70 element.

### FEATURES

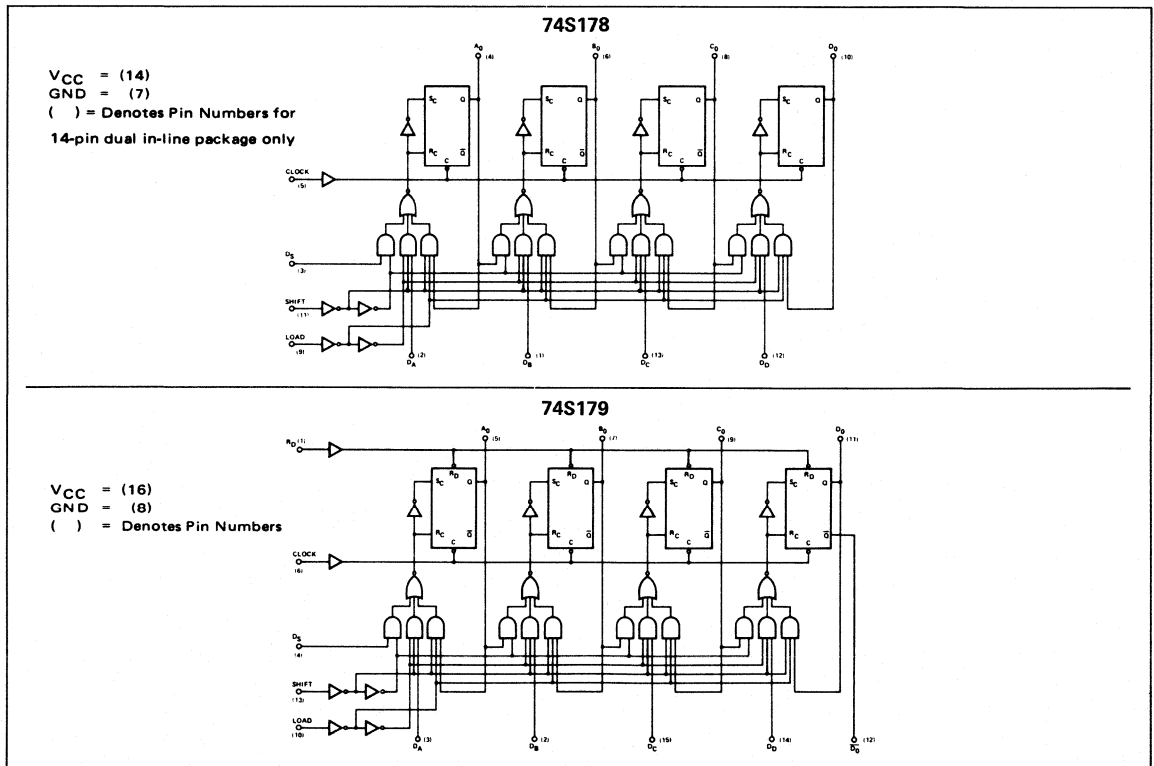
- SCHOTTKY-CLAMPED TTL STRUCTURE
- PNP INPUTS
- SYNCHRONOUS LOAD
- SHIFT RIGHT/LEFT CAPABILITY
- HOLD MODE

### ELECTRICAL CHARACTERISTICS

Transfer Rate	60 MHz (Typ)
Input Load Current (Max)	
$I_{in}''0''$	400 $\mu$ A
$I_{in}''1''$	25 $\mu$ A
Output Current	
$I_{out}''0''$	20mA @ 0.5V
$I_{out}''1''$	1mA @ 2.7V

### LOGIC DIAGRAM

SEE 82S70-71 DATA SHEETS



### DIGITAL 54/74 TTL SERIES

#### DESCRIPTION

These Schottky-clamped high-speed arithmetic/logic units, functionally identical to the S54181 and N74181, perform 16 binary arithmetic operations on two 4-bit words with a full look-ahead carry scheme as propagate and generate terms are available at the P and G outputs. Typical performance is 19 nanoseconds add time for a 16-bit word when used with the S54S182 or N74S182 carry look-ahead.

Typical addition times are shown in Table III. The S54S181/N74S181 can replace the S54181/N74181 in most existing systems for significant performance upgrading as they are functionally and mechanically interchangeable.

The S54S181 and N74S181 will also perform the 16 possible functions on two Boolean variables without the use of external circuitry. The carry circuit is inhibited for logic functions.

The S54S181 and N74S181 will accommodate active-high or active-low data if the pin designations are interpreted as shown below:

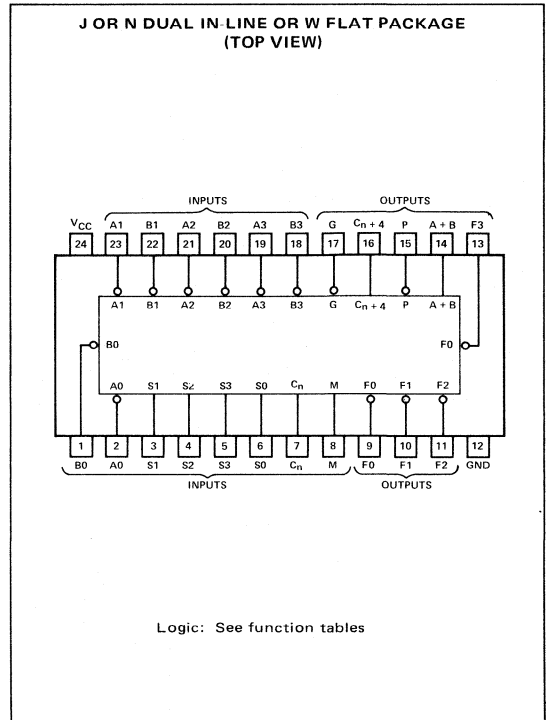
Subtraction is accomplished by 1's complement addition where the 1's complement of the subtrahend is generated internally. The resultant output is  $A-B-1$  which requires an end-around or forced carry to provide  $A-B$ .

Mode of operation (arithmetic or logic) is controlled by the mode-control (M) input. Complete functions for active-high and active-low data are shown in Tables I and II.

Typical average power dissipation is 600 milliwatts, or approximately 8 milliwatts per equivalent gate. The S54S181 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74S181 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

For additional descriptive information and typical connection schemes, see the S54181/N74181 data sheet

#### PIN CONFIGURATION



#### FEATURES

- SIGNIFICANT IMPROVEMENT IN ADD TIMES OVER S54181/N74181
- TYPICAL ADD TIME FOR 16 BITS OF 19 ns USING S54S182, N74S182 LOOK-AHEAD
- S54S181 IS GUARANTEED FOR OPERATION OVER THE FULL MILITARY TEMPERATURE RANGE OF  $-55^{\circ}\text{C}$  TO  $125^{\circ}\text{C}$
- FULLY COMPATIBLE WITH MOST TTL FUNCTIONS INCLUDING MSI

PIN NUMBER	2	1	23	22	21	20	19	18	9	10	11	13	7	16	15	17
Active-high data (Table I)	A <sub>0</sub>	B <sub>0</sub>	A <sub>1</sub>	B <sub>1</sub>	A <sub>2</sub>	B <sub>2</sub>	A <sub>3</sub>	B <sub>3</sub>	F <sub>0</sub>	F <sub>1</sub>	F <sub>2</sub>	F <sub>3</sub>	C <sub>n</sub>	C <sub>n+4</sub>	X	Y
Active-low data (Table II)	$\overline{A_0}$	$\overline{B_0}$	$\overline{A_1}$	$\overline{B_1}$	$\overline{A_2}$	$\overline{B_2}$	$\overline{A_3}$	$\overline{B_3}$	$\overline{F_0}$	$\overline{F_1}$	$\overline{F_2}$	$\overline{F_3}$	C <sub>n</sub>	C <sub>n+4</sub>	$\overline{P}$	$\overline{G}$

**SIGNETICS ARITHMETIC LOGIC UNITS/FUNCTION GENERATORS ■ S54S181, N74S181**

**TABLE I**

SELECTION S <sub>3</sub> S <sub>2</sub> S <sub>1</sub> S <sub>0</sub>				ACTIVE-HIGH DATA		
				M = H LOGIC FUNCTIONS	M = L: ARITHMETIC OPERATIONS	
					C <sub>n</sub> = 0 = H (no carry)	C <sub>n</sub> = 1 = L (with carry)
L	L	L	L	$F = \overline{A}$	F = A	F = A plus 1
L	L	L	H	$F = \overline{A + B}$	F = A + B	F = (A + B) plus 1
L	L	H	L	$F = \overline{AB}$	F = A + $\overline{B}$	F = (A + $\overline{B}$ ) plus 1
L	L	H	H	F = 0	F = minus 1 (2's complement)	F = zero
L	H	L	L	$F = \overline{AB}$	F = A plus $\overline{AB}$	F = A plus $\overline{AB}$ plus 1
L	H	L	H	$F = \overline{B}$	F = (A + B) plus $\overline{AB}$	F = (A + B) plus $\overline{AB}$ plus 1
L	H	H	L	$F = A \oplus B$	F = A minus B minus 1	F = A minus B
L	H	H	H	$F = A\overline{B}$	F = $\overline{AB}$ minus 1	F = $\overline{AB}$
H	L	L	L	$F = \overline{A} + B$	F = A plus AB	F = A plus AB plus 1
H	L	L	H	$F = \overline{A} \oplus B$	F = A plus B	F = A plus B plus 1
H	L	H	L	F = B	F = (A + $\overline{B}$ ) plus AB	F = (A + $\overline{B}$ ) plus AB plus 1
H	L	H	H	F = AB	F = AB minus 1	F = AB
H	H	L	L	F = 1	F = A plus A*	F = A plus A plus 1
H	H	L	H	$F = A + \overline{B}$	F = (A + B) plus A	F = (A + B) plus A plus 1
H	H	H	L	F = A + B	F = (A + $\overline{B}$ ) plus A	F = (A + $\overline{B}$ ) plus A plus 1
H	H	H	H	F = A	F = A minus 1	F = A

\*Each bit is shifted to the next more significant position.

**TABLE II**

SELECTION S <sub>3</sub> S <sub>2</sub> S <sub>1</sub> S <sub>0</sub>				ACTIVE-LOW DATA		
				M = H LOGIC FUNCTIONS	M = L: ARITHMETIC OPERATIONS	
					C <sub>n</sub> = 0 = L (no carry)	C <sub>n</sub> = 1 = H (with carry)
L	L	L	L	$F = \overline{A}$	F = A minus 1	F = A
L	L	L	H	$F = \overline{AB}$	F = AB minus 1	F = AB
L	L	H	L	$F = \overline{A} + B$	F = $\overline{AB}$ minus 1	F = $\overline{AB}$
L	L	H	H	F = 1	F = minus 1 (2's complement)	F = zero
L	H	L	L	$F = \overline{A + B}$	F = A plus (A + $\overline{B}$ )	F = A plus (A + $\overline{B}$ ) plus 1
L	H	L	H	$F = \overline{B}$	F = AB plus (A + $\overline{B}$ )	F = AB plus (A + $\overline{B}$ ) plus 1
L	H	H	L	$F = A \oplus B$	F = A minus B minus 1	F = A minus B
L	H	H	H	$F = A + \overline{B}$	F = A + $\overline{B}$	F = (A + $\overline{B}$ ) plus 1
H	L	L	L	$F = \overline{AB}$	F = A plus (A + B)	F = A plus (A + B) plus 1
H	L	L	H	$F = A \oplus B$	F = A plus B	F = A plus B plus 1
H	L	H	L	F = B	F = $\overline{AB}$ plus (A + B)	F = $\overline{AB}$ plus (A + B) plus 1
H	L	H	H	F = A + B	F = A + B	F = (A + B) plus 1
H	H	L	L	F = 0	F = A plus A*	F = A plus A plus 1
H	H	L	H	$F = A\overline{B}$	F = AB plus A	F = AB plus A plus 1
H	H	H	L	F = AB	F = $\overline{AB}$ plus A	F = $\overline{AB}$ plus A plus 1
H	H	H	H	F = A	F = A	F = A plus 1

\*Each bit is shifted to the next more significant position.

**RECOMMENDED OPERATING CONDITIONS**

	S54S181			N74S181			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20	Low logic level		10	
	Low logic level		10	High logic level		20	
Operating free-air temperature, T <sub>A</sub>	-55		125	0		70	°C



# SIGNETICS ARITHMETIC LOGIC UNITS/FUNCTION GENERATORS ■ S54S181, N74S181

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*	MIN	TYP**	MAX	UNIT
$V_{IH}$	High-level input voltage		2			V
$V_{IL}$	Low-level input voltage				0.8	V
$V_I$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.2	V
$V_{OH}$	High-level output voltage, any output except A = B	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$	N54S181	2.5	3.4	V
			S74S181	2.7	3.4	
$I_{OH}$	High-level output current, A = B output only	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, V_{OH} = 5.5 \text{ V}$			250	$\mu\text{A}$
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 20 \text{ mA}$			0.5	V
$I_I$	Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1	mA
$I_{IH}$	High-level input current	mode input	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$		50	$\mu\text{A}$
		any A or B input		150		
		any S input		200		
		carry input		250		
$I_{IL}$	Low-level input current	mode input	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$		-2	mA
		any A or B input		-6		
		any S input		-8		
		carry input		-10		
$I_{OS}$	Short-circuit output current, any output except A = B	$V_{CC} = \text{MAX}$	-40		-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{MAX}, T_A = 125^\circ \text{C}$	N54S181		135	mA
		See Note 1	N pkg only			
		$V_{CC} = \text{MAX},$ See Note 1	N54S181	120	159	
			S74S181	120	220	

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}$ .

‡Not more than one output should be shorted at a time.

NOTE 1:  $I_{CC}$  is measured for the following conditions:

- a.  $S_0$  through  $S_3, M,$  and A inputs are at 4.5 V, all other inputs are grounded, and all outputs are open.
- b.  $S_0$  through  $S_3$  and M are at 4.5 V, all other inputs are grounded, and all outputs are open.

SWITCHING CHARACTERISTICS,  $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}, N = 10, I_{CL} = 15 \text{ }\mu\text{F}, R_L = 280 \text{ }\Omega$  see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	$C_n$	$C_{n+4}$		7	10.5		ns
$t_{PHL}$				7	10.5		
$t_{PLH}$	Any A or B	$C_{n+4}$	$M = 0 \text{ V}, S_0 = S_3 = 4.5 \text{ V}, S_1 = S_2 = 0 \text{ V (SUM mode)}$	12.5	18.5		ns
$t_{PHL}$				12.5	18.5		
$t_{PLH}$	Any A or B	$C_{n+4}$	$M = 0 \text{ V}, S_0 = S_3 = 0 \text{ V}, S_1 = S_2 = 4.5 \text{ V (DIFF mode)}$	15.5	23		ns
$t_{PHL}$				15.5	23		
$t_{PLH}$	$C_n$	Any F	$M = 0 \text{ V (SUM or DIFF mode)}$	7	12		ns
$t_{PHL}$				7	12		
$t_{PLH}$	Any A or B	G	$M = 0 \text{ V}, S_0 = S_3 = 4.5 \text{ V}, S_1 = S_2 = 0 \text{ V (SUM Mode)}$	8	12		ns
$t_{PHL}$				7.5	12		
$t_{PLH}$	Any A or B	G	$M = 0 \text{ V}, S_0 = S_3 = 0 \text{ V}, S_1 = S_2 = 4.5 \text{ V (DIFF mode)}$	10.5	15		ns
$t_{PHL}$				10.5	15		
$t_{PLH}$	Any A or B	P	$M = 0 \text{ V}, S_0 = S_3 = 4.5 \text{ V}, S_1 = S_2 = 0 \text{ V (SUM mode)}$	7.5	12		ns
$t_{PHL}$				7.5	12		
$t_{PLH}$	Any A or B	P	$M = 0 \text{ V}, S_0 = S_3 = 0 \text{ V}, S_1 = S_2 = 4.5 \text{ V (DIFF mode)}$	10.5	15		ns
$t_{PHL}$				10.5	15		
$t_{PLH}$	Any A or B	Any F	$M = 0 \text{ V}, S_0 = S_3 = 4.5 \text{ V}, S_1 = S_2 = 0 \text{ V (SUM mode)}$	11	16.5		ns
$t_{PHL}$				11	16.5		
$t_{PLH}$	Any A or B	Any F	$M = 0 \text{ V}, S_0 = S_3 = 0 \text{ V}, S_1 = S_2 = 4.5 \text{ V (DIFF mode)}$	14	20		ns
$t_{PHL}$				14	22		
$t_{PLH}$	Any A or B	Any F	$M = 4.5 \text{ V (logic mode)}$	14	20		ns
$t_{PHL}$				14	22		
$t_{PLH}$	Any A or B	A = B	$M = 0 \text{ V}, S_0 = S_3 = 0 \text{ V}, S_1 = S_2 = 4.5 \text{ V (DIFF mode)}$	15	23		ns
$t_{PHL}$				20	30		

$t_{PLH}$  = propagation delay time, low to high-level output

$t_{PHL}$  = propagation delay time, low to high-level output

NOTE 2: Load circuits and waveforms are shown on p. 2-293.

Typical addition times for various configurations are given in the table below. Subtraction times are typically 3 nanoseconds longer than summation times. For typical look-ahead configurations, see the S54181/N74181 data sheet in this catalog.

TABLE III  
TYPICAL ADDITION TIMES

NUMBER OF BITS	ADDITION TIMES				PACKAGE COUNT		CARRY METHOD BETWEEN ALL'S
	USING S54S181 AND S54S182	USING S54S181 AND S54S182	USING S54S181 AND S54S182	ARITHMETIC/LOGIC UNITS	LOOK-AHEAD CARRY GENERATORS		
1 to 4	11 ns	11 ns	24 ns	1	1	NONE	
5 to 8	18 ns	18 ns	36 ns	2	1	RIPPLE	
9 to 16	19 ns	24 ns	36 ns	3 or 4	1	FULL LOOK-AHEAD	
17 to 64	28 ns	45 ns	60 ns	5 to 16	2 to 5	FULL LOOK-AHEAD	

#### DESCRIPTION

These high-performance bidirectional shift registers are functionally and mechanically identical to the N54194 and S74194, however, with a typical shift frequency of 110 megahertz the Schottky-clamped versions can be used in very high-speed systems, or can be substituted for the N54194/S74194 to upgrade the performance of most existing systems. The universal shift register has four distinct modes of operation, namely:

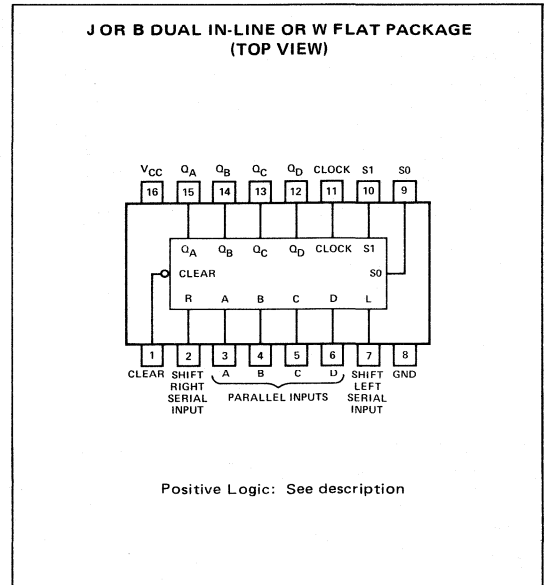
	MODE CONTROL	
	S1	S0
Parallel (Broadside) Load	H	H
Shift Right (In the direction $Q_A$ toward $Q_D$ )	L	H
Shift Left (In the direction $Q_D$ toward $Q_A$ )	H	L
Hold (recirculate) data	L	L

In the parallel-load mode, data is loaded into the associated flip-flop and appears at the outputs after the positive transition of the clock input. During loading, serial data flow is inhibited. Shift right is accomplished synchronously with the rising edge of the clock pulse when S0 is high and S1 is low. Serial data for this mode is entered at the shift-right data input. When S0 is low and S1 is high, data shifts left synchronously and new data is entered at the shift-left serial input. Data is recirculated when both mode control inputs are low. For added flexibility the mode controls can be changed independently of the clock.

These four-bit shift registers are compatible with most other TTL and DTL logic families. All inputs are buffered to lower the drive requirements to one normalized Series 54S/74S load, and input clamping diodes minimize switching transients to simplify system design. With the equivalent of 46 gates on the monolithic chip, typical power dissipation is less than 10 milliwatts per equivalent gate.

The N54S194 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the S74S194 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### PIN CONFIGURATION



#### FEATURES

- SCHOTTKY-CLAMPED TO ACHIEVE TYPICAL MAXIMUM SHIFT FREQUENCY OF 110 MHz
- FUNCTIONALLY AND MECHANICALLY IDENTICAL TO N54194, S74194 AND CAN BE USED TO UPGRADE EXISTING SYSTEMS WITH SIGNIFICANT IMPROVEMENT IN SPEED
- FULLY COMPATIBLE WITH MOST OTHER TTL AND DTL CIRCUITS
- N54S194 OPERATES OVER FULL MILITARY TEMPERATURE RANGE OF  $-55^{\circ}\text{C}$  TO  $125^{\circ}\text{C}$
- FOR USE IN HIGH-PERFORMANCE: ACCUMULATORS/PROCESSORS, SERIAL-TO-PARALLEL AND PARALLEL-TO-SERIAL CONVERTERS

# SIGNETICS 4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTERS ■ S54S194, N74S194

## RECOMMENDED OPERATING CONDITIONS

PARAMETER			54S194			74S194			UNITS	
			MIN	NOM	MAX	MIN	NOM	MAX		
Supply voltage, $V_{CC}$			4.5	5	5.5	4.75	5	5.25	V	
High-level output current, $I_{OH}$					-1			-1	mA	
Low-level output current, $I_{OL}$					20			20	mA	
Clock frequency, $f_{clock}$			0		70	0		70	MHz	
Width of clock pulse, $t_{w(clock)}$			7			7			ns	
Width of clear pulse, $t_{w(clear)}$			12			12			ns	
Setup time, $t_{setup}$	PA	Mode control	8			8			ns	
		Serial and parallel data	5			5			ns	
		Clear inactive-state	9			9			ns	
Hold time at any input, $t_{hold}$			3			3			ns	
Operating free-air temperature, $T_A$			-55			125			70	°C

## ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS*	54S194			74S194			UNITS
		MIN	TYP**	MAX	MIN	TYP**	MAX	
$V_{IH}$ High-level input voltage		2			2			V
$V_{IL}$ Low-level input voltage				0.8			0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18\text{mA}$			-1.5			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -1\text{mA}$	2.5	3.4		2.7	3.4		V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 20\text{mA}$			0.5			0.5	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			50			50	μA
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$			-2			-2	mA
$I_{OS}$ Short-circuit output current†	$V_{CC} = \text{MAX}$	-40		-100	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ See Note 2		85	135		85	135	mA
	$V_{CC} = \text{MAX},$ See Note 2							
	$T_A = 125^\circ\text{C},$ SN54S194N SN54S194W			99 110				

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

\*\* All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}.$

† Not more than one output should be shorted at a time, and duration of short-circuit should not exceed one second.

### NOTE 2:

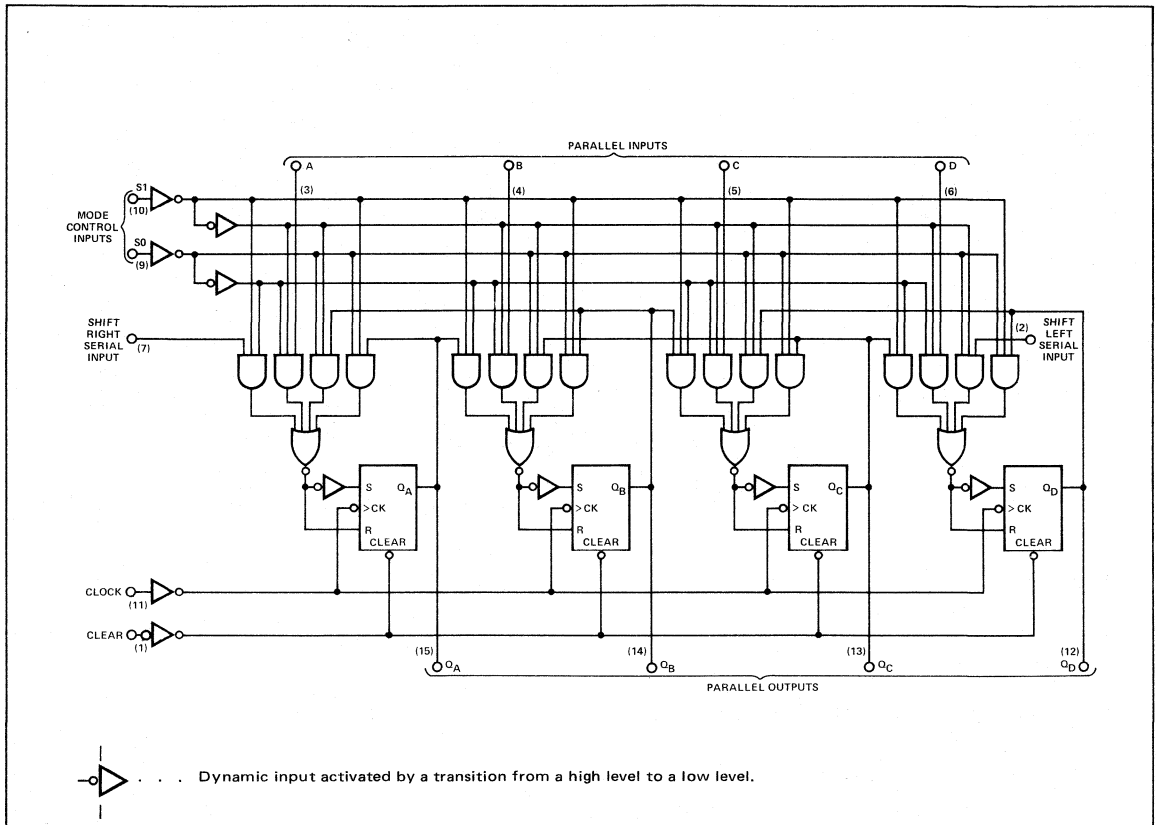
With all outputs open, inputs A through D grounded, and 4.5V applied to S0, S1, clear, and the serial inputs,  $I_{CC}$  is tested with a momentary GND, then 4.5V, applied to clock.

## SWITCHING CHARACTERISTICS $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$

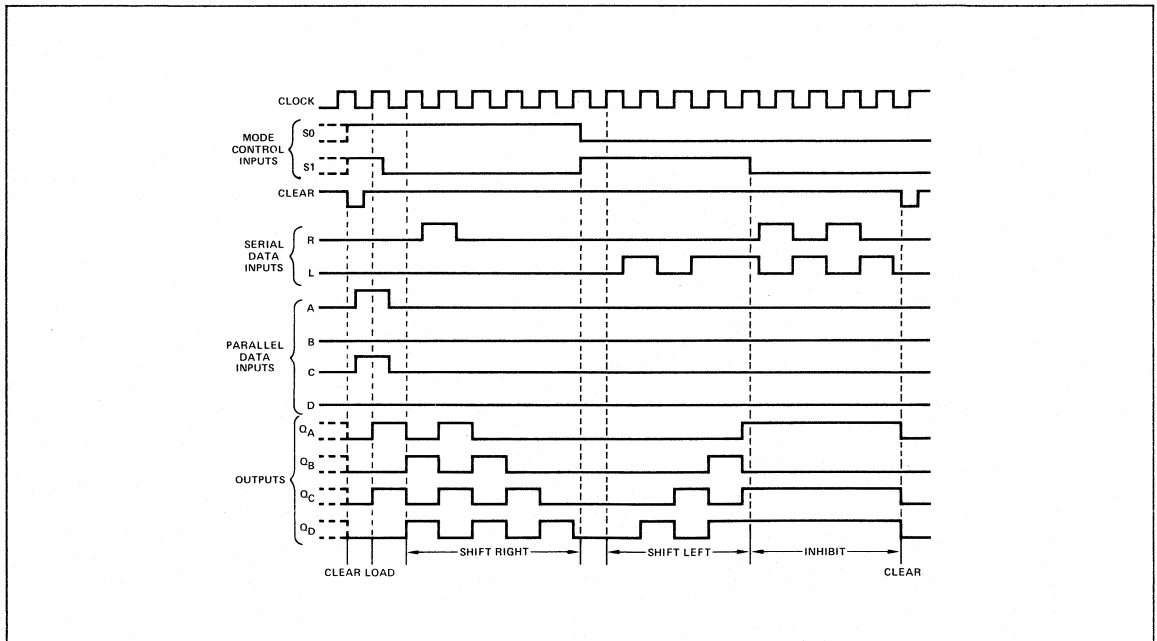
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum clock frequency	$C_L = 15\text{pF}, R_L = 280\Omega,$ See Figure 1	70	105		MHz
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear			12.5	18.5	ns
$t_{PLH}$ Propagation delay time, low-to-high-level output from clock		4	8	12	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clock		4	11	16.5	ns

# SIGNETICS 4-BIT BIDIRECTIONAL UNIVERSAL SHIFT REGISTERS ■ S54S194, N74S194

## FUNCTIONAL BLOCK DIAGRAM



## TYPICAL CLEAR, LOAD, RIGHT-SHIFT, INHIBIT, AND CLEAR SEQUENCES



#### DESCRIPTION

These high-performance 4-bit registers feature a 110-megahertz typical maximum shift-frequency which makes them particularly attractive for very high-speed data processing systems. As the pin assignments are the same as the S54195 and N74195, existing systems can in most cases be upgraded merely by utilizing the Schottky-clamped versions. The registers have two modes of operation:

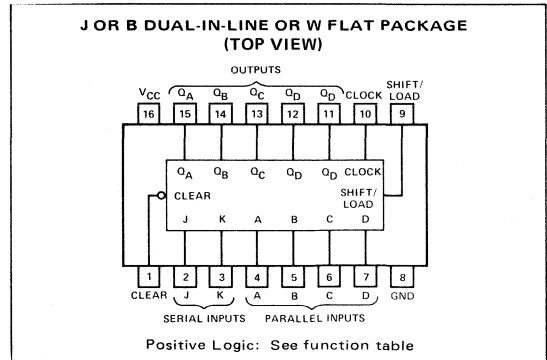
Parallel (Broadside) Load  
Shift (In the direction  $Q_A$  toward  $Q_D$ )

Parallel loading is accomplished by applying the four bits of data and taking the shift/load control input low. The data is loaded into the associated flip-flop and appears at the outputs after the positive transition of the clock input. During loading, serial data flow is inhibited.

Shifting is accomplished synchronously when the shift/load control input is high. Serial data for this mode is entered at the J-K inputs. These inputs permit the first stage to perform as a J-K, D-, or T-type flip-flop as shown in the function table.

These shift registers are fully compatible with other TTL families. All inputs are buffered to lower the drive requirements to one normalized Series 54S/74S load, including the clock input. The S54S195 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the N74S195 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

#### PIN CONFIGURATION



#### FEATURES

- SCHOTTKY-CLAMPED TO ACHIEVE TYPICAL MAXIMUM SHIFT FREQUENCY OF 110 MHz
- FUNCTIONALLY AND MECHANICALLY IDENTICAL TO N54195, S74195 AND CAN BE USED TO UPGRADE EXISTING DESIGNS WITH SIGNIFICANT IMPROVEMENT IN SPEED
- FULLY COMPATIBLE WITH OTHER TTL CIRCUITS
- N54S195 OPERATES OVER FULL MILITARY TEMPERATURE RANGE OF  $-55^{\circ}\text{C}$  TO  $125^{\circ}\text{C}$
- USE IN HIGH-PERFORMANCE:  
ACCUMULATORS/PROCESSORS  
SERIAL-TO-PARALLEL,  
PARALLEL-TO-SERIAL CONVERTERS

#### FUNCTION TABLE

INPUTS									OUTPUTS				
CLEAR	SHIFT/ LOAD	CLOCK	SERIAL		PARALLEL				$Q_A$	$Q_B$	$Q_C$	$Q_D$	$\bar{Q}_D$
			J	$\bar{K}$	A	B	C	D					
L	X	X	X	X	X	X	X	X	L	L	L	L	H
H	L	$\uparrow$	X	X	A	B	C	D	A	B	C	D	$\bar{D}$
H	H	L	X	X	X	X	X	X	$Q_{A0}$	$Q_{B0}$	$Q_{C0}$	$Q_{D0}$	$\bar{Q}_{D0}$
H	H	$\uparrow$	L	H	X	X	X	X	$Q_{A0}$	$Q_{A0}$	$Q_{B0}$	$Q_{C0}$	$\bar{Q}_{C0}$
H	H	$\uparrow$	H	H	X	X	X	X	L	$Q_{A0}$	$Q_{B0}$	$Q_{C0}$	$\bar{Q}_{C0}$
H	H	$\uparrow$	H	L	X	X	X	X	H	$Q_{A0}$	$Q_{B0}$	$Q_{C0}$	$\bar{Q}_{C0}$
H	H	$\uparrow$	H	L	X	X	X	X	$Q_{A0}$	$Q_{A0}$	$Q_{B0}$	$Q_{B0}$	$\bar{Q}_{C0}$

H = High level (steady state)

L = Low level (steady state)

X = Irrelevant (any input, including transitions)

$\uparrow$  = Transition from low to high level

A, B, C, D, = The level of steady state input at A, B, C, or D respectively

$Q_{A0}$ ,  $Q_{B0}$ ,  $Q_{C0}$ ,  $Q_{D0}$  = the level of  $Q_A$ ,  $Q_B$ ,  $Q_C$ , or  $Q_D$  respectively before the indicated steady state input conditions were established.

# SIGNETICS 4-BIT PARALLEL-ACCESS SHIFT REGISTERS ■ S54S195, N74S195

## RECOMMENDED OPERATING CONDITIONS

PARAMETER		54195			74195			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$		4.5	5	5.5	4.75	5	5.25	V
High-level output current, $I_{OH}$				-800			-800	$\mu$ A
Low-level output current, $I_{OL}$				16			16	mA
Clock frequency, $f_{clock}$		0		30	0		30	MHz
Width of clock input pulse, $t_{w(clock)}$		16			16			ns
Width of clear input pulse, $t_{w(clear)}$		12			12			ns
Setup time, $t_{setup}$ (see Figure 1)	Shift/load	25			25			ns
	Serial and parallel data	15			15			
	Clear inactive-state	25			25			
Shift/load release time, $t_{release}$ (see Figure 1)				10			10	ns
Serial and parallel data hold time, $t_{hold}$ (see Figure 1)		0			0			ns
Operating free-air temperature, $T_A$		-55		125	0		70	$^{\circ}$ C

## ELECTRICAL CHARACTERISTICS over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS *	MIN	TYP*	MAX	UNIT
$V_{IH}$ High-level input voltage			2		V
$V_{IL}$ Low-level input voltage				0.8	V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -12\text{mA}$			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -800\mu\text{A}$	2.4	3.4		V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OL} = 16\text{mA}$		0.2	0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5\text{V}$			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.4\text{V}$			40	$\mu$ A
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4\text{V}$			-1.6	mA
$I_{OS}$ Short-circuit output current <sup>†</sup>	$V_{CC} = \text{MAX}$	54195	-20	-57	mA
		74195	-18	-57	
$I_{CC}$ Supply current	$V_{CC} = \text{MAX},$ See Note 2		39	63	mA

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^{\circ}\text{C}$ .

Not more than one output should be shorted at a time.

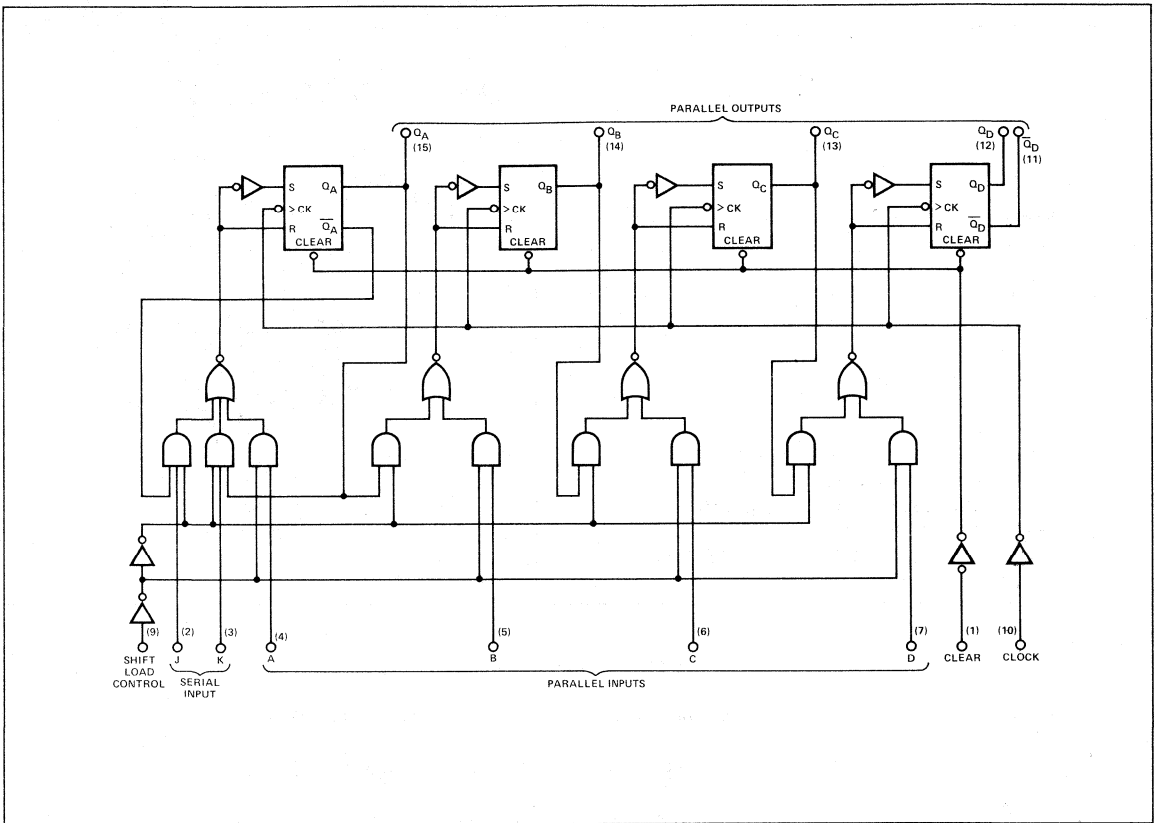
### NOTE:

- With all outputs open, shift/load grounded, and 4.5V applied to the J, K, and data inputs,  $I_{CC}$  is measured by applying a momentary ground, followed by 4.5V, to clear and then applying a momentary ground, followed by 4.5V, to clock.

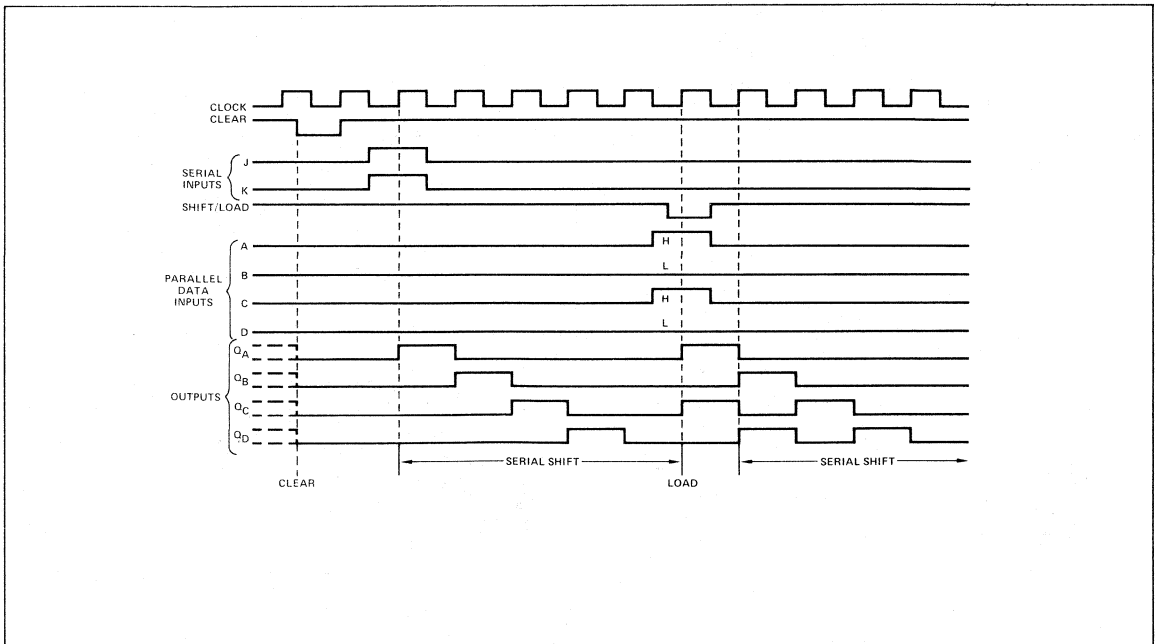
## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$f_{max}$ Maximum clock frequency	$C_L = 15\text{pF}$ $R_L = 400\Omega$	30	39		MHz	
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear			19	30	ns	
$t_{PLH}$ Propagation delay time, low-to-high-level output from clock			6	14	22	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clock			7	17	26	ns

FUNCTIONAL BLOCK DIAGRAM



TYPICAL CLEAR, SHIFT, AND LOAD SEQUENCES



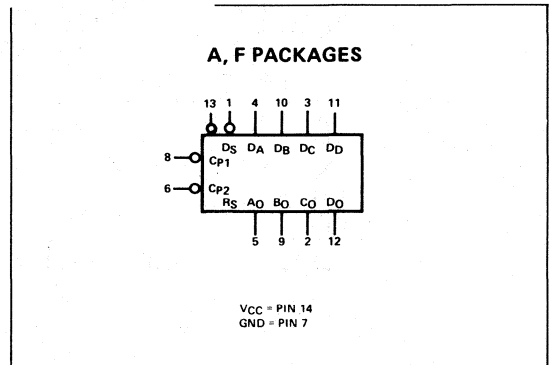
### DESCRIPTION

The 74S196 Decade Counter and 74S197 Binary Counter are very high speed versions of the popular 74S196 Decade and 74S197 Binary Counters. They are multifunctional MSI building blocks capable of being used in counting frequency synthesis, digital integration where high speed is essential.

### FEATURES

- 100 MHz TYPICAL COUNT FREQUENCY
- HIGH IMPEDANCE PNP INPUTS
- VARIABLE MODULUS,  $\div 2, 4, 5, 8, 10,$  and  $16$
- STROBED PARALLEL ENTRY
- PIN REPLACEABLE for the 8290/8291, 74196/74197

### LOGIC SYMBOL

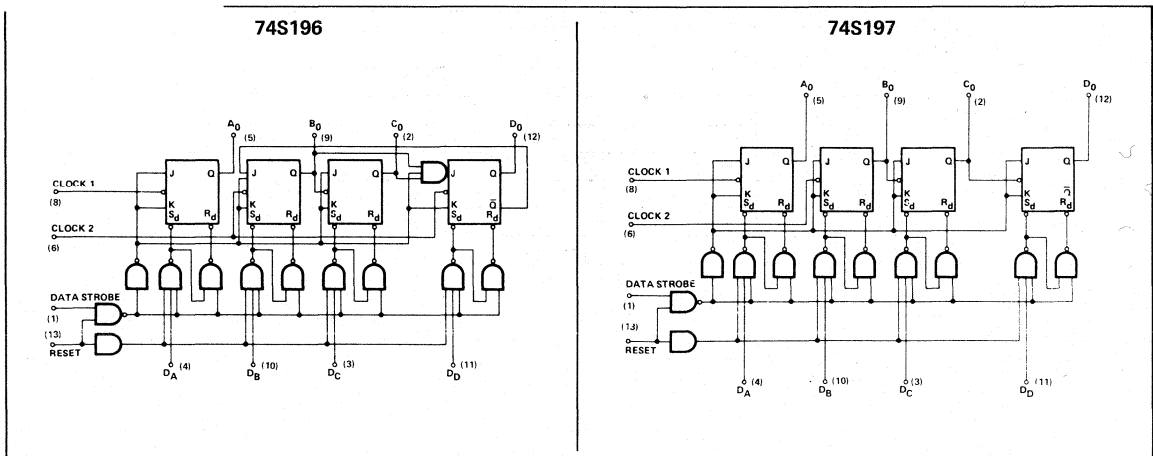


### PIN DESIGNATIONS

SEE 82S90-91 DATA SHEETS

CP <sub>1</sub>	Clock input to counter first stage (active low going edge)
CP <sub>2</sub>	Clock input to counter last three stages (active low going edge)
DS	Data Strobe Input for enabling data entry
RS	Reset Input for resetting all stages and outputs to zero
DA, DB, DC, DD	Data Inputs
AO, BO, CO, DO	Data Outputs

### LOGIC DIAGRAMS





#### DESCRIPTION

These monolithic Schottky-barrier-diode-clamped TTL circuits are high-performance multiplexers which are significantly faster than the S54253/N74253. As an example, the two-gate-level delay from the data inputs to the output is only 8.5 nanoseconds maximum compared to 18 or 23 nanoseconds maximum for the standard-speed part. Overall, the guaranteed delay times for the S54S253/N74S253 represent approximately a 100% improvement over standard TTL with only a 12% increase in maximum d-c power consumption. In many cases, the S54S253 or N74S253 can plug into existing systems designed for S54153 or N74153.

These data selectors/multiplexers are fully compatible for use with most standard, high-speed, and low-power TTL and DTL circuits. Each diode-clamped input represents only one normalized Series 54S/74S load, and full fan-out to 10 normalized Series 54S/74S loads is available from each of the outputs at low logic levels. A fan-out to 20 normalized Series 54S/74S loads is provided at high logic levels to facilitate connection of unused inputs to used inputs. Typical power dissipation is 225 milliwatts.

#### ABSOLUTE MAXIMUM RATINGS (over operating free-air temperature range unless otherwise noted)

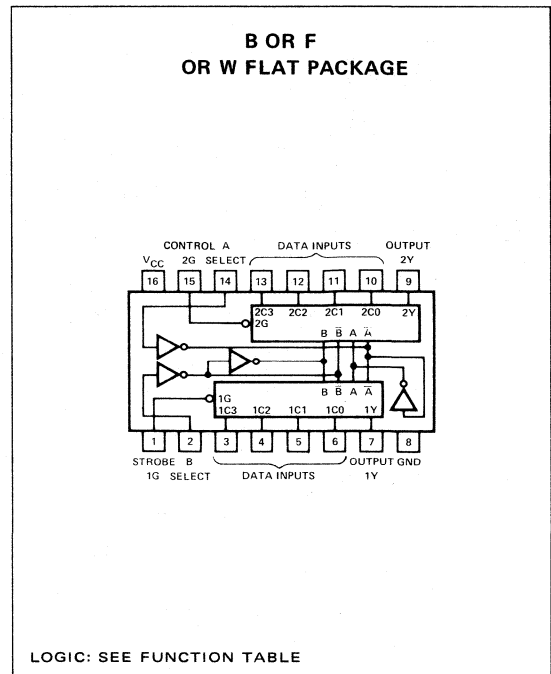
Supply voltage, $V_{CC}$ (See Note 1)	7 V
Input voltage (See Note 1)	5.5 V
Operating free-air temperature range:	
S54S253 Circuits	-55°C to 125°C
N74S253 Circuits	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

#### RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S253			N74S253			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		20	Low logic level		10	
	Low logic level		10	High logic level		20	
Operating free-air temperature range, $T_A$	-55		125	0		70	C

#### PIN CONFIGURATION



#### FUNCTION TABLE

SELECT INPUTS		DATA INPUTS				STROBE	OUTPUT
B	A	C0	C1	C2	C3	G	Y
X	X	X	X	X	X	H	Z
L	L	L	X	X	X	L	L
L	L	H	X	X	X	L	H
L	H	X	L	X	X	L	L
L	H	X	H	X	X	L	H
H	L	X	X	L	X	L	L
H	L	X	X	H	X	L	H
H	A	X	X	X	L	L	L
H	H	X	X	X	H	L	H

Address inputs A and B are common to both sections.  
H = High level, L = Low level, X = Irrelevant.

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP**	MAX	UNIT
V <sub>IH</sub> High-level input voltage		2			V
V <sub>IL</sub> Low-level input voltage				0.8	V
V <sub>I</sub> Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA			-1.2	V
V <sub>OH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = -1 mA	Series 54S	2.4	3.4	V
		Series 74S	2.7	3.4	
V <sub>OL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 20 mA			0.5	V
I <sub>I</sub> Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V			1	mA
I <sub>IH</sub> High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7 V			50	μA
I <sub>IL</sub> Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5 V			-2	mA
I <sub>OS</sub> Short-circuit output current ‡	V <sub>CC</sub> = MAX	-40		-100	mA
I <sub>CCL</sub> Supply current, low level output	V <sub>CC</sub> = MAX, See Note 2		45	70	mA
H 12-1 Output Leakage	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 2.40V			50	mA
H 12-0 Output Leakage	V <sub>CC</sub> = MAX, V <sub>OUT</sub> = 0.4V			-50	mA

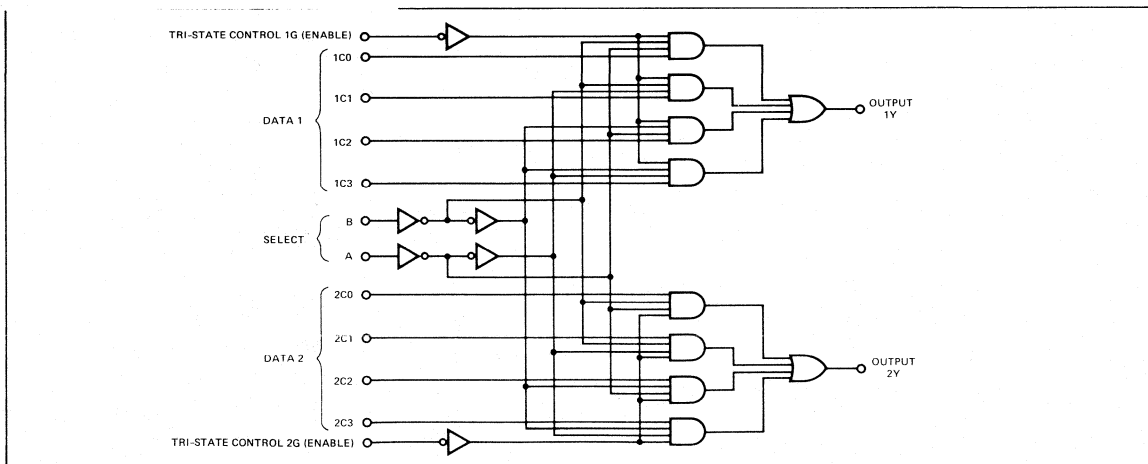
- \* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.
- \*\* All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.
- ‡ Not more than one output should be shorted at a time.
- NOTE: 2: I<sub>CCL</sub> is measured with the outputs open and all inputs grounded.

SWITCHING CHARACTERISTICS, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C, N = 10

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Data	Y	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 280 Ω		6	9	ns
t <sub>PHL</sub>	Data	Y			6	9	ns
t <sub>PLH</sub>	Select	Y			11.5	18	ns
t <sub>PHL</sub>	Select	Y			12	18	ns
t <sub>PH</sub>	Control	Y			6	13	ns
t <sub>PL</sub>	Control	Y			7	14	ns
t <sub>PLZ</sub>	Control	Y			6	14	ns
t <sub>PHZ</sub>	Control	Y			5	8.5	ns

- t<sub>PLH</sub> = Propagation delay time, low-to-high-level output.
- t<sub>PHL</sub> = Propagation delay time, high-to-low-level output.

FUNCTIONAL BLOCK DIAGRAM

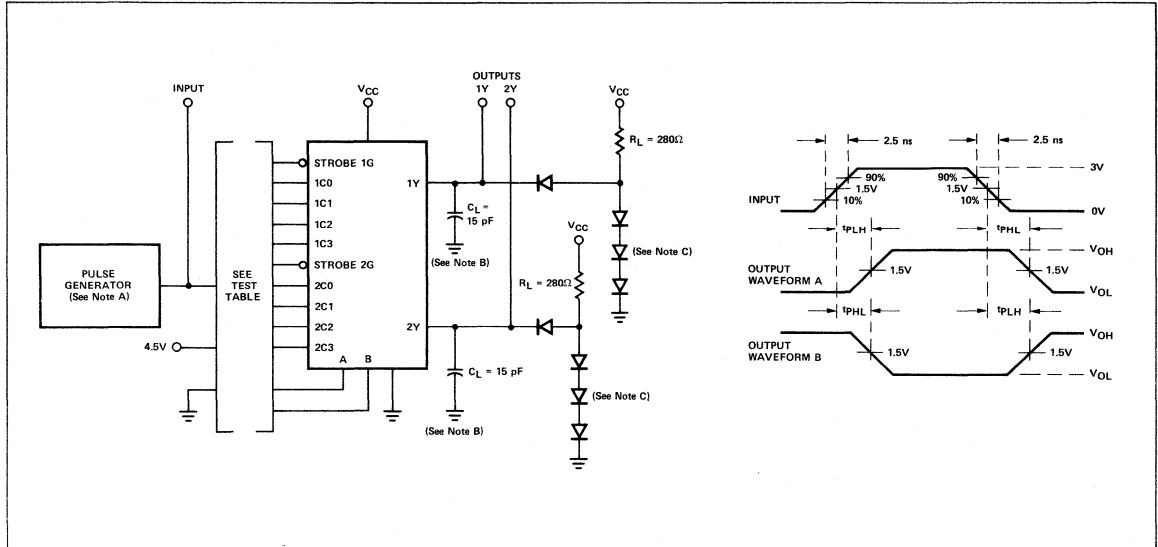


TEST TABLE

INPUTS							OUTPUT Y WAVEFORM
B	A	C0	C1	C2	C3	G	
GND	GND	INPUT	X	X	X	GND	A
GND	4.5V	X	INPUT	X	X	GND	A
4.5V	GND	X	X	INPUT	X	GND	A
4.5V	4.5V	X	X	X	INPUT	GND	A
GND	INPUT	GND	4.5V	X	X	GND	A
INPUT	GND	GND	X	4.5V	X	GND	A
GND	GND	4.5V	X	X	X	INPUT	B

X = Irrelevant

PARAMETER MEASUREMENT INFORMATION



NOTES:

1. The pulse generator has the following characteristics: PRR = 1 MHz, duty cycle = 50%, and  $Z_{out} \approx 50\Omega$ .
2.  $C_L$  includes probe and jig capacitance.
3. All diodes are 1N3064.

#### DESCRIPTION

These Schottky-clamped high-performance multiplexers feature three-state outputs which can interface directly with and drive data lines of bus-organized systems. With all but one of the common outputs disabled (at a high-impedance state) the low impedance of the single enabled output will drive the bus line to a high or low logic level.

This three-state output feature means that n-bit (paralleled) data selectors with up to 258 sources can be implemented for data buses. It also permits the use of standard TTL registers for data retention throughout the system.

The typical propagation delay times from data input to output average only 4.8 nanoseconds for the S54S257, N74S157 and only 4 nanoseconds for the S54S258, N74S258. Also, to minimize the possibility that two outputs will attempt to take a common bus to opposite logic levels, the output-enable circuitry is designed such that the output disable times are shorter than the output enable times.

#### FEATURES

- TRI-STATE OUTPUTS INTERFACE DIRECTLY WITH SYSTEM BUS
- SCHOTTKY-CLAMPED FOR SIGNIFICANT IMPROVEMENT IN A-C PERFORMANCE
- FULLY COMPATIBLE WITH MOST TTL FUNCTIONS INCLUDING MSI
- SAME PIN ASSIGNMENTS AS S54S157, N74S157 AND S54S158, N74S158
- PROVIDES BUS INTERFACE FROM MULTIPLE SOURCES IN HIGH-PERFORMANCE SYSTEMS
- N54S257 AND N54S258 ARE GUARANTEED FOR OPERATION OVER THE FULL MILITARY TEMPERATURE RANGE OF  $-55^{\circ}\text{C}$  TO  $125^{\circ}\text{C}$

#### FUNCTION TABLE

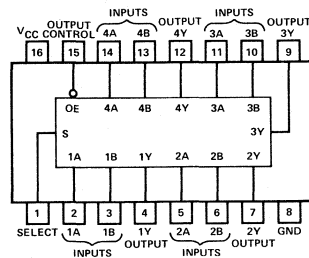
		INPUTS		OUTPUT Y	
OUTPUT CONTROL	SELECT	A	B	N54S257 S74S257	N54S258 S74S258
H	X	X	X	Z	Z
L	L	L	X	L	H
L	L	H	X	H	L
L	H	X	L	L	H
L	H	X	H	H	L

H = High level, L = Low level, X = Irrelevant, Z = High impedance (off)

#### PIN CONFIGURATION

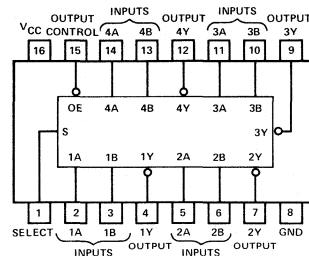
##### J OR B DUAL IN-LINE OR W FLAT PACKAGE (TOP VIEW)

##### S54S257, N74S257



Positive Logic: See function table

##### S54S258, N74S258



Positive Logic: See function table

# SIGNETICS QUADRUPLE 2-LINE TO 1-LINE ■ S54S257, S54S258, N74S257, N74S258

## RECOMMENDED OPERATING CONDITIONS

PARAMETER	S54S257, S54S258			N74S257, N74S258			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
Normalized fan-out from each output, N	High logic level		40	130			
	Low logic level		10	10			
High-level output current, $I_{OH}$			2	6.5			mA
Operating free-air temperature, $T_A$	-55		125	0		70	°C

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	S54S257, S54S258		N74S257, N74S258		UNIT
		MIN	TYP** MAX	MIN	TYP** MAX	
$V_{IH}$ High-level input voltage		2		2		V
$V_{IL}$ Low-level input voltage		0.8		0.8		V
$V_I$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$	-1.2		-1.2		V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, \text{ Series } 54\text{S}$	2.5	3.4	2.5	3.4	V
	$V_{IL} = 0.8 \text{ V}, I_{OH} = \text{MAX}, \text{ Series } 74\text{S}$	2.4	3.2	2.4	3.2	
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_{IL} = 0.8 \text{ V}, I_{OL} = 20 \text{ mA}$	0.5		0.5		V
$I_{O(\text{off})}$ Off-state (high-impedance state) output current	$V_{CC} = \text{MAX}, V_O = 2.4 \text{ V}$	50		50		$\mu\text{A}$
	$V_{CC} = \text{MAX}, V_O = 0.4 \text{ V}$	-50		-50		
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$	1		1		mA
$I_{IH}$ High-level input current	S input	100		100		$\mu\text{A}$
	Any other	50		50		
$I_{IL}$ Low-level input current	S input	-4		-4		mA
	Any other	-2		-2		
$I_{OS}$ Short circuit output current‡	$V_{CC} = \text{MAX}$	-40	-100	-40	-100	mA
$I_{CC}$ Supply current	All outputs high	44	68	36	56	mA
	All outputs low	60	93	52	81	
	All outputs off	64	99	56	87	

\*For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\*All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}$ .

‡Not more than one output should be shorted at a time and duration of the short circuit test should not exceed one second.

NOTE 1:  $I_{CC}$  is measured with all outputs open and all possible inputs grounded while achieving the stated output conditions.

## SWITCHING CHARACTERISTICS, $V_{CC} = 5 \text{ V}, T_A = 25^\circ \text{C}$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	S54S257, N74S257			S54S258, N74S258			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
$t_{PLH}$	Data	Any	$C_L = 15 \text{ pF}, R_L = 280 \Omega, \text{ See Note } 4$	5	7.5		4	6	ns	
$t_{PHL}$				4.5	6.5		4	6		
$t_{PLH}$	Select	Any		8.5			8	12	ns	
$t_{PHL}$				8.5			7.5	12		
$t_{ZH}$	Output Control	Any		13	19.5		13	19.5	ns	
$t_{ZL}$				14	21		14	21		
$t_{HZ}$	Output Control	Any	$C_L = 5 \text{ pF}, \text{ See Note } 2$	5.5	8.5		5.5	8.5	ns	
$t_{LZ}$				9	14		9	14		

$t_{PLH}$  = Propagation delay time, low-to-high-level output

$t_{PHL}$  = Propagation delay time, high-to-low-level output

$t_{ZH}$  = Output enable time to high level

$t_{ZL}$  = Output enable time to low level

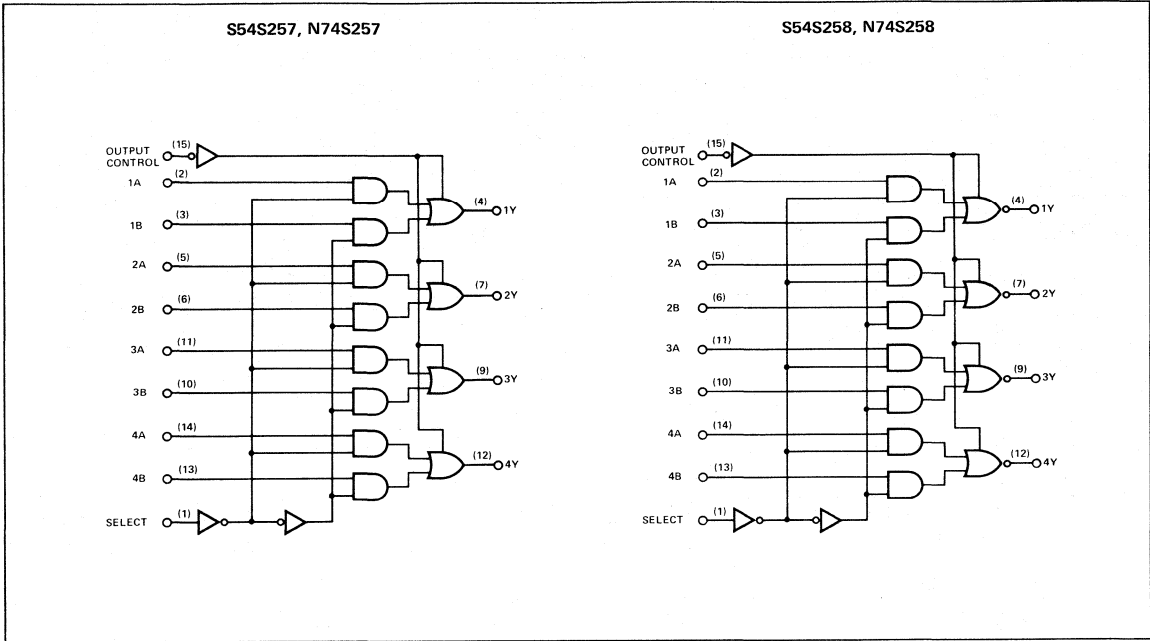
$t_{HZ}$  = Output disable time from high level

$t_{LZ}$  = Output disable time from low level

NOTE 2: Load circuit and waveforms are shown on page 2-293

**SIGNETICS QUADRUPLE 2-LINE TO 1-LINE ■ S54S257, S54S258, N74S257, N74S258**

**FUNCTIONAL BLOCK DIAGRAMS**



### DESCRIPTION

The 9300 is a synchronous 4 bit shift register designed to perform functions such as storage, shifting, counting and serial code conversion. It has assertion outputs on each stage and a negation output on the last stage, an overriding asynchronous master reset, JK input configuration, and a synchronous parallel load facility.

Data entry is synchronous with the registers changing state after each low to high transition of the clock. With the parallel enable low the parallel inputs determine the next condition of the shift register. When the parallel enable input is high the shift register performs a one bit shift to the right, with data entering the first stage flip-flop through JK inputs. By tying the two inputs together D type entry is obtained.

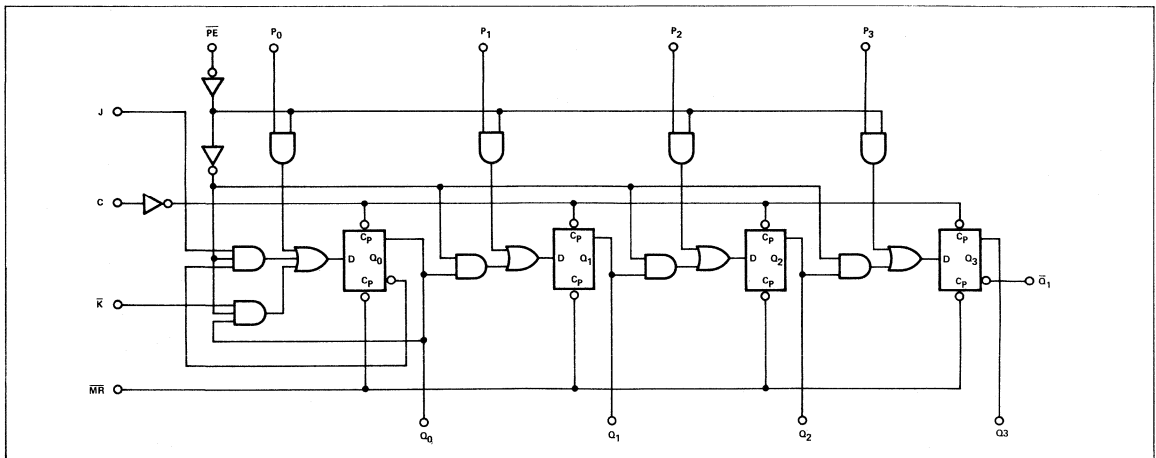
The asynchronous active low master reset when activated overrides all other input conditions and clears the register.

### TRUTH TABLE FOR SERIAL ENTRY

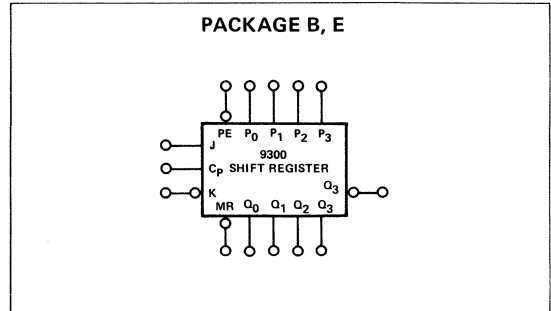
J	$\bar{K}$	Q at t
L	L	L
L	H	Q at t (no change)
H	L	$\bar{Q}$ at t (toggles)
H	H	H

$\overline{PE}$  = HIGH,  $\overline{MR}$  = HIGH. (n + 1) Indicates State After Next Clock.

### SCHEMATIC



### PIN CONFIGURATIONS



### PIN NAMES

$\overline{PE}$	Parallel Enable (Active Low) Input
$P_0, P_1, P_2, P_3$	Parallel Inputs
J	First Stage J (Active High) Input
$\bar{K}$	First Stage K (Active Low) Input
$C_p$	Clock (Active High Going Edge) Input
$\overline{MR}$	Master Reset (Active Low) Input
$Q_0, Q_1, Q_2, Q_3$	Parallel Outputs
$\bar{Q}_3$	Complementary Last Stage Output

### CHARACTERISTICS

TYPICAL SPEED	25 MHz Shifting Frequency
TYPICAL DELAY	$C_p$ to Q 23 ns
PACKAGE	16 Pin Dip or Flat Pack
TYPICAL POWER	
DISSIPATION	300 mW

ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTICS	LIMITS				UNITS	CONDITIONS		
		0°C		+25°C				+75°C	
		MIN.	MAX.	MIN.	TYP. MAX	MIN.	MAX.		
V <sub>OH</sub>	Output High Voltage	2.4		2.4	3.0	2.4		Volts	V <sub>CC</sub> = 4.75V, I <sub>OH</sub> = -0.36 mA
V <sub>OL</sub>	Output Low Voltage		0.45		0.2 0.45		0.45	Volts	V <sub>CC</sub> = 5.25V, I <sub>OL</sub> = 0.6 mA
V <sub>IH</sub>	Input High Voltage	1.9		1.8		1.6		Volts	V <sub>CC</sub> = 4.75V, I <sub>OL</sub> = 8.5 mA Guaranteed Input high threshold for all inputs
V <sub>IL</sub>	Input Low Voltage		0.85		0.85		0.85	Volts	Guaranteed input low threshold for all inputs
I <sub>F</sub>	Input Load Current J, $\bar{K}$ , MR, P <sub>0</sub> , P <sub>1</sub> , P <sub>2</sub> & P <sub>3</sub>	-1.6		-1.0	-1.6	-1.6		mA	V <sub>CC</sub> = 5.25V
		-1.41		-0.9	-1.41	-1.41		mA	V <sub>CC</sub> = 4.75V, V <sub>F</sub> = 0.45V
I <sub>R</sub>	Input Leakage Current J, $\bar{K}$ , MR, P <sub>0</sub> , P <sub>1</sub> , P <sub>2</sub> & P <sub>3</sub>			15	60		60	μA	V <sub>CC</sub> = 5.25V, V <sub>R</sub> = 4.5V

SWITCHING CHARACTERISTICS (T<sub>A</sub> = 25°C)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	CONDITIONS & COMMENTS
t <sub>pd+</sub>	Turn Off Delay		20	35	ns	V <sub>CC</sub> = 5.0V, C <sub>L</sub> = 15pF
t <sub>pd-</sub>	Turn On Delay		25	45	ns	
f <sub>sr</sub>	Shift Right Frequency	15	25		MHz	V <sub>CC</sub> = 5.0 V, C <sub>L</sub> = 15 pF
CP <sub>pw</sub>	Clock Pulse Width	35	15		ns	V <sub>CC</sub> = 5.0 V C <sub>L</sub> = 15 pF
t <sub>s</sub>	Set-up Time	35	17		ns	
t <sub>r</sub>	Release Time		16	0	ns	
t <sub>s</sub> (PE)	Set-up Time for PE	45	26		ns	
t <sub>r</sub> (PE)	Release Time for PE		25	10	ns	
t <sub>pd-</sub> (MR)	Reset Time for MR		35		ns	
t <sub>rec</sub> (MR)	Recovery Time for MR		20		ns	
MR <sub>pw</sub>	Min Reset Pulse Width		15		ns	

NOTES:

SET-UP TIME: t<sub>s</sub> is defined as the minimum time required for the logic level to be present at the logic input prior to the clock transition from low to high in order for the flip-flop(s) to respond.

RELEASE TIME: t<sub>r</sub> is defined as the maximum time allowed for the logic level to be present at the logic input prior to the clock transition from low to high in order for the flip-flop(s) not to respond.

RECOVERY TIME FOR MR: t<sub>rec</sub>(MR) is defined as the minimum time required between the end of the reset pulse and the clock transition from low to high in order for the flip-flop(s) to respond to the clock.

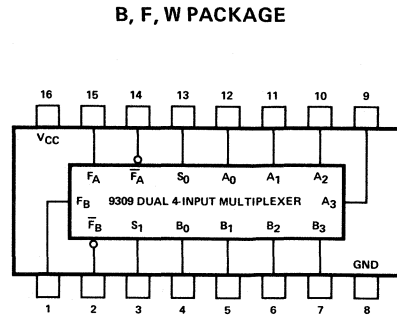


### DESCRIPTION

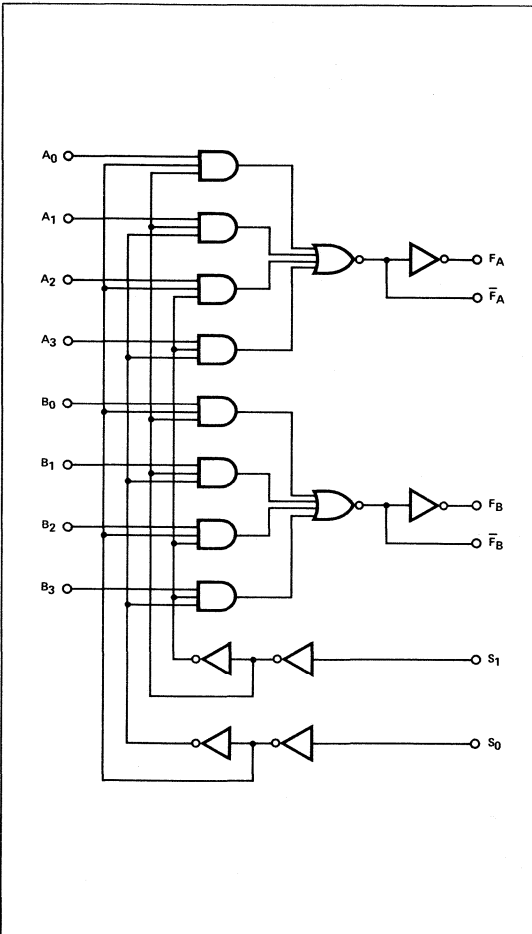
The Signetics 9309 is a direct replacement for U6B 9309. It consists of two 4 input multiplexers with common input select logic. It allows two bits of data to be switched in parallel to the appropriate outputs from two 4 bit data sources. Both polarities of outputs are available.

An obvious use of the 9309 is the moving of data from a group of registers to a common output buss. The particular register from which the data comes is determined by the state of the select inputs. The 9309 can also generate two functions of three variables. This is useful for implementing random gating functions.

### PIN CONFIGURATION



### LOGIC DIAGRAM



PIN NAMES		LOADING
$S_0, S_1$	Common Select Inputs	1
<b>Multiplexer A</b>		
$A_0, A_1, A_2, A_3$	Multiplexer Inputs	1
$F_A$	Multiplexer Output	10
$\bar{F}_A$	Complementary Multiplexer Output	9
<b>Multiplexer B</b>		
$B_0, B_1, B_2, B_3$	Multiplexer Inputs	1
$F_B$	Multiplexer Output	10
$\bar{F}_B$	Complementary Multiplexer Output	9
<b>CHARACTERISTICS</b>		
TYPICAL DELAYS	S to F	24ns
	I to F	9ns
PACKAGE	16 Pin Dip or Flat Pack	
TYPICAL POWER DISSIPATION	150 mW	

### ABSOLUTE MAXIMUM RATINGS (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
VCC Pin Potential to Ground Pin	-0.5 V to +7 V
Voltage Applied to Output when Output is High	0 V to +VCC
Input Voltage (DC) (See Note 1)	-0.5 V to +5.5 V
Input Current (DC) (See Note 1)	-30 mA to +5 mA
Current into Output when Output is Low	+30 mA

#### NOTE:

1. Either Input Voltage limit or Input Current limit is sufficient to protect the inputs.

**FUNCTIONAL DESCRIPTION**

The 9309 dual four input multiplexer is a member of the Signetics family of compatible Medium Scale Integrated (MSI) digital building blocks. It provides this family with the ability to select two bits of either data or control from up to four sources, in one package.

The 9309 dual four input multiplexer is the logical implementation of a two-pole four-position switch, with the position of the switch being set by the logic levels supplied to the two select inputs. Both assertion and negation outputs are provided for both multiplexers. The logic equations for the outputs are shown below:

$$F_A = A_0 \cdot S_1 \cdot S_0 + A_1 \cdot S_1 \cdot S_0 + A_2 \cdot S_1 \cdot S_0 + A_3 \cdot S_1 \cdot S_0$$

$$F_B = B_0 \cdot S_1 \cdot S_0 + B_1 \cdot S_1 \cdot S_0 + B_2 \cdot S_1 \cdot S_0 + B_3 \cdot S_1 \cdot S_0$$

A common use of the 9309 would be the moving of data from a group of registers to a common output buss. The particular register from which the data came would be determined by the state of the select inputs. The 9309 can also generate any two functions of three variables. This is useful for implementing random gating functions.

**TRUTH TABLE**

SELECT INPUTS		INPUTS				OUTPUTS	
S <sub>0</sub>	S <sub>1</sub>	A <sub>0</sub>	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	F <sub>A</sub>	$\bar{F}_A$
L	L	L	X	X	X	L	H
L	L	H	X	X	X	H	L
H	L	X	L	X	X	L	H
H	L	X	H	X	X	H	L
L	H	X	X	L	X	L	H
L	H	X	X	H	X	H	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	H	L

S <sub>0</sub>	S <sub>1</sub>	B <sub>0</sub>	B <sub>1</sub>	B <sub>2</sub>	B <sub>3</sub>	F <sub>B</sub>	$\bar{F}_B$
L	L	L	X	X	X	L	H
L	L	H	X	X	X	H	L
H	L	X	L	X	X	L	H
H	L	X	H	X	X	H	L
L	H	X	X	L	X	L	H
L	H	X	X	H	X	H	L
H	H	X	X	X	L	L	H
H	H	X	X	X	H	H	L

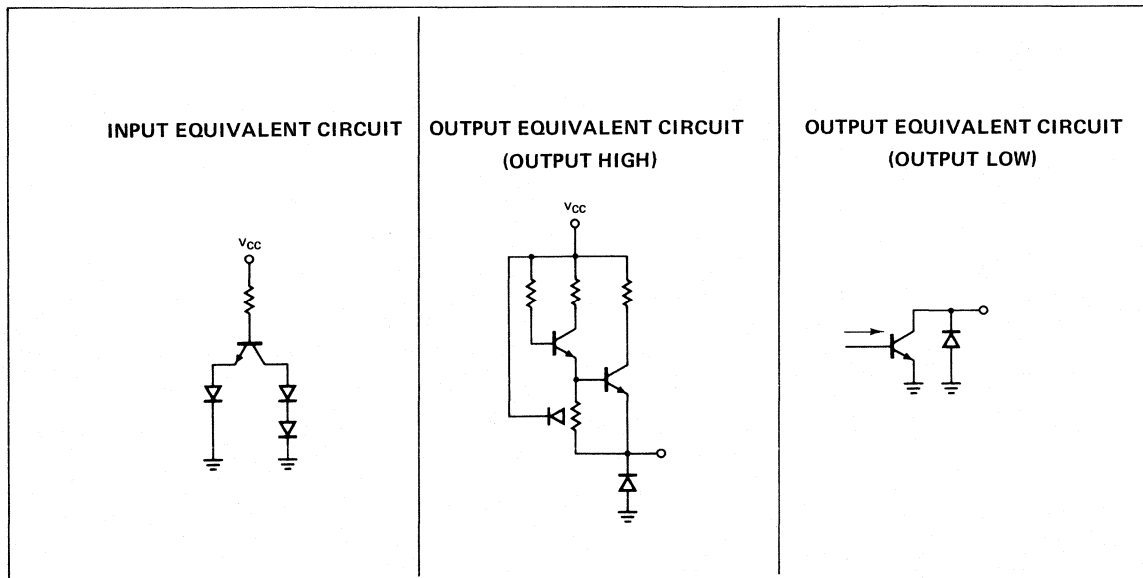
L = low voltage level  
 H = high voltage level  
 X = either high or low logic level

**LOADING RULES**

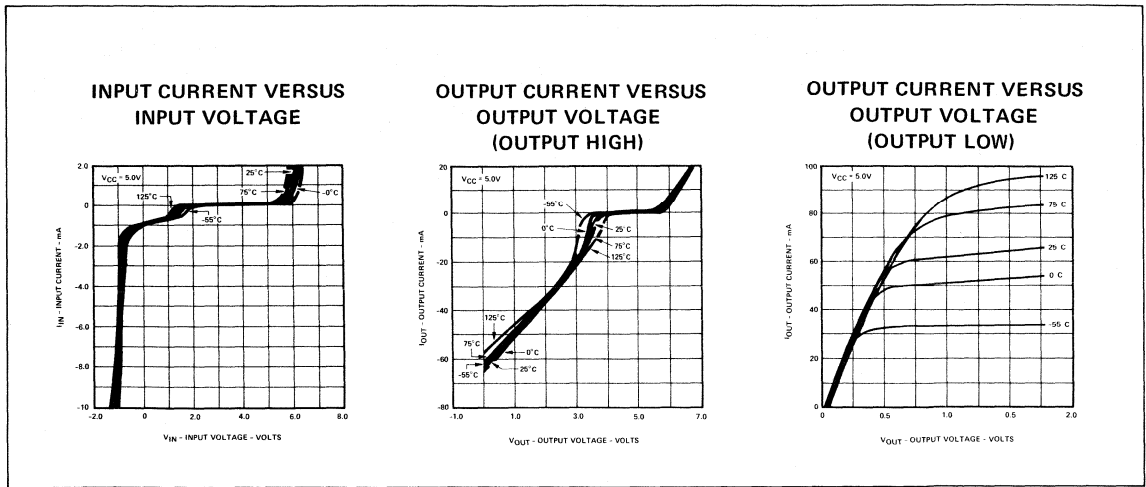
(1L. = 1 TTL gate input load)

INPUTS	LOADING	
A <sub>0</sub> , A <sub>1</sub> , A <sub>2</sub> , A <sub>3</sub> B <sub>0</sub> , B <sub>1</sub> , B <sub>2</sub> , B <sub>3</sub> S <sub>0</sub> , S <sub>1</sub>	1L.	
OUTPUTS	FANOUT AT LOGIC LEVEL	
	HIGH	LOW
F <sub>A</sub> , F <sub>B</sub>	20L	10L.
$\bar{F}_A$ , $\bar{F}_B$	18L	9L.

**TYPICAL INPUT AND OUTPUT CHARACTERISTICS**



TYPICAL INPUT AND OUTPUT CHARACTERISTICS (Cont'd)



ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		$-55^{\circ}C$		$+25^{\circ}C$		$+125^{\circ}C$				
		MIN	MAX	MIN	TYP	MAX	MIN			MAX
$V_{OH}$	Output High Voltage	2.4		2.4	2.7		2.4		Volts	$V_{CC} = 4.5V$ $I_{OH} = -1.2mA$ (Pins 1 & 15) $V_{CC} = 4.5V$ $I_{OH} = -1.08mA$ (Pins 2 & 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{OL}$	Output Low Voltage		0.4		0.21	0.4		0.4	Volts	$V_{CC} = 5.5V$ $I_{OL} = 16.0mA$ (Pins 1 & 15) $I_{OL} = 14.4mA$ (Pins 2 & 14) $V_{CC} = 4.5V$ $I_{OL} = 12.4mA$ (Pins 1 & 15) $I_{OL} = 11.2mA$ (Pins 2 & 14) Inputs at threshold voltages ( $V_{IL}$ or $V_{IH}$ ) as per truth table
$V_{IH}$	Input High Voltage	2.0		1.7			1.4		Volts	Guaranteed input high threshold for all inputs
$V_{IL}$	Input Low Voltage		0.8			0.9		0.8	Volts	Guaranteed input low threshold for all inputs
$I_F$ (all inputs)	Input Load Current		-1.6		-1.1	-1.6		-1.6	mA	$V_{CC} = 5.5V$ $V_F = 0.4V$
			-1.24		-0.85	-1.24		-1.24	mA	$V_{CC} = 4.5V$ Input selected
$I_R$ (all inputs)	Input Leakage Current				15	60		60	$\mu A$	$V_{CC} = 5.5V$ $V_R = 4.5V$ Input not selected
$I_{PDH}$	$V_{CC}$ Current		40		30	40		40	mA	$V_{CC} = 5.0V$ All inputs high
$t_{pd+}$ ( $S_0$ to $Z_a$ )	Switching Speed				24	32			ns	$V_{CC} = 5.0V$ , $C_L = 15pF$ , See Figure 8
$t_{pd-}$ ( $S_0$ to $Z_a$ )	Switching Speed				24	32			ns	

\*Pulse tested

ELECTRICAL CHARACTERISTICS

SYMBOL	CHARACTERISTICS	LIMITS						UNITS	CONDITIONS	
		0°C		+25°C		+75°C				
		MIN	MAX	MIN	TYP	MAX	MIN	MAX		
V <sub>OH</sub>	Output High Voltage	2.4		2.4	3.0		2.4		Volts	V <sub>CC</sub> = 4.75V I <sub>OH</sub> = -1.2mA (Pins 1 & 15) V <sub>CC</sub> = 4.75V I <sub>OH</sub> = -1.08 mA (Pins 2 & 14) Inputs at threshold voltages (V <sub>IL</sub> or V <sub>IH</sub> ) as per truth table
V <sub>OL</sub>	Output Low Voltage		0.45		0.21	0.45		0.45	Volts	V <sub>CC</sub> = 5.25V I <sub>OL</sub> = 16.0mA (Pins 1 & 15) I <sub>OL</sub> = 14.4mA (Pins 2 & 14) V <sub>CC</sub> = 4.75V I <sub>OL</sub> = 14.1mA (Pins 1 & 15) I <sub>OL</sub> = 12.7mA (Pins 2 & 14) Inputs at threshold voltages (V <sub>IL</sub> or V <sub>IH</sub> ) as per truth table
V <sub>IH</sub>	Input High Voltage	1.9		1.8			1.6		Volts	Guaranteed input high threshold for all inputs
V <sub>IL</sub>	Input Low Voltage		0.85			0.85		0.85	Volts	Guaranteed input low threshold for all inputs
I <sub>F</sub> (all inputs)	Input Load Current		-1.6		-1.0	-1.6		-1.6	mA	V <sub>CC</sub> = 5.25V V <sub>F</sub> = 0.45V
			-1.41		-0.91	-1.41		-1.41	mA	V <sub>CC</sub> = 4.75V Input selected
I <sub>R</sub> (all inputs)	Input Leakage Current				15	60		60	μA	V <sub>CC</sub> = 5.25V V <sub>R</sub> = 4.5V Input not selected
I <sub>PDH</sub>	V <sub>CC</sub> Current		43		30	43		43	mA	V <sub>CC</sub> = 5.0V All inputs high
t <sub>pd+</sub> (S <sub>0</sub> to Z <sub>a</sub> )	Switching Speed				24	36			ns	V <sub>CC</sub> = 5.0V, C <sub>L</sub> = 15pF
t <sub>pd-</sub> (S <sub>0</sub> to Z <sub>a</sub> )	Switching Speed				24	36			ns	

\*Pulse tested

### DESCRIPTION

The TTL/Monostable 9602 Dual Retriggerable, Resettable Monostable Multivibrator provides an output pulse whose duration and accuracy is a function of external timing components. The 9602 has excellent immunity to noise on the  $V_{CC}$  and ground lines. The 9602 uses TTL inputs and outputs for high speed and high fanout capability and is compatible with all members of the Fairchild TTL family.

### FEATURES

- 72 ns TO  $\infty$  OUTPUT WIDTH RANGE
- RETRIGGERABLE 0 TO 100% DUTY CYCLE
- TTL INPUT GATING—LEADING OR TRAILING EDGE TRIGGERING
- COMPLEMENTARY TTL OUTPUTS
- OPTIONAL RETRIGGER LOCK-OUT CAPABILITY
- PULSE WIDTH COMPENSATED FOR  $V_{CC}$  AND TEMPERATURE VARIATIONS
- RESETTABLE

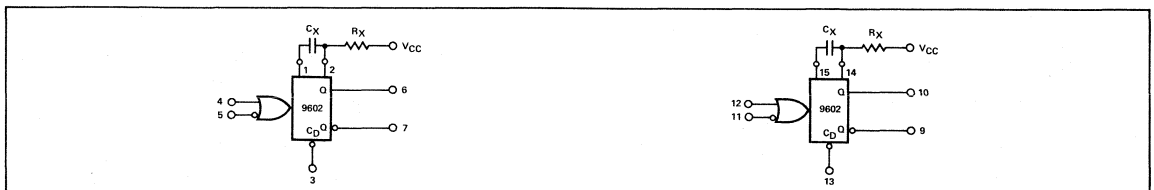
**ABSOLUTE MAXIMUM RATINGS** (above which the useful life may be impaired)

Storage Temperature	-65°C to +150°C
Temperature (Ambient) Under Bias	-55°C to +125°C
$V_{CC}$ Pin Potential to Ground (See Note 1)	-0.5 V to +8.0 V
Input Voltage (dc) (See Note 2)	-0.5 V to +5.5 V
Input Current (See Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output When Output is HIGH	-0.5 V to + $V_{CC}$ value
Current Into Output When Output is LOW	50 mA

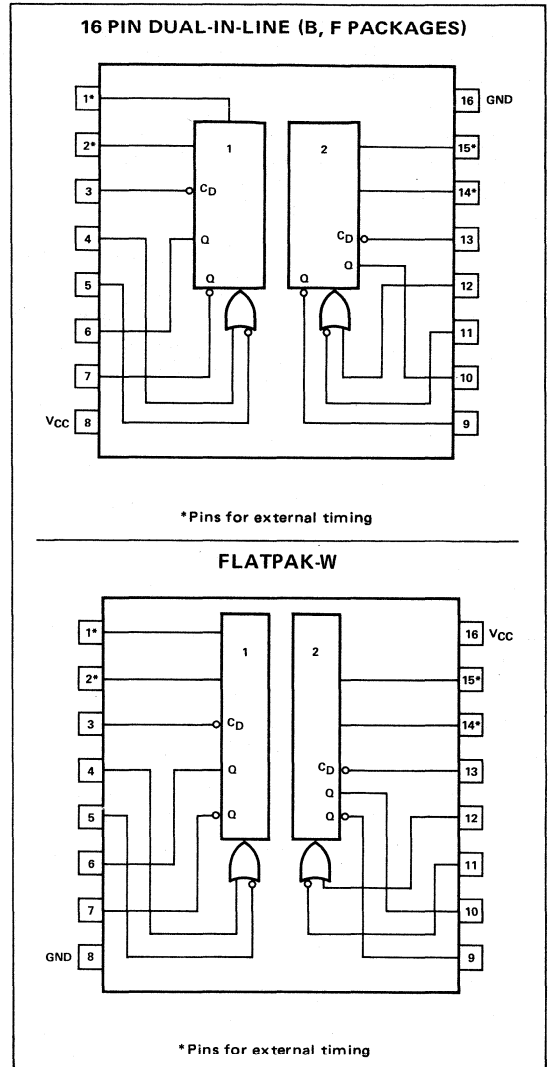
### NOTES:

1. The maximum  $V_{CC}$  value of 8.0 volts is not the primary factor in determining the maximum  $V_{CC}$  which may be applied to a number of interconnected devices. The voltage at a HIGH output is approximately 1  $V_{BE}$  below the  $V_{CC}$  voltage, so the primary limit on the  $V_{CC}$  is that the voltage at any input may not go above 5.5 V unless the current is limited. This effectively limits the system  $V_{CC}$  to approximately 7.0 volts.
2. Because of the input clamp diodes, excess current can be drawn out of the inputs if the dc input voltage is more negative than -0.5 V. The diode is designed to clamp off large negative ac swings associated with fast fall times and long lines. This maximum rating is intended only to limit the steady state input voltage and current.

### LOGIC DIAGRAM



### PIN CONFIGURATIONS (Top View)



**FUNCTIONAL DESCRIPTION**

The 9602 dual resettable, retriggerable monostable multivibrator has two inputs per function, one active LOW and one active HIGH. This allows leading edge or trailing edge triggering. The TTL inputs make triggering independent of input transition times. When input conditions for triggering are met, a new cycle starts and the external capacitor is rapidly discharged and then allowed to charge. An input cycle time shorter than the output cycle time will retrigger the 9602 and result in a continuous true output. The output pulse may be terminated at any time by connecting the reset pin to a logic level LOW. Active pullups are provided on the outputs for good drive capability into capacitive loads. Retriggering may be inhibited by typing Q output to an active level LOW input or the Q output to the active level HIGH input.

**OPERATION RULES**

- An external resistor ( $R_X$ ) and external capacitor ( $C_X$ ) are required as shown in the Logic Diagram.
- The value of  $R_X$  may vary from 5.0 k $\Omega$  to 50 k $\Omega$  for 0 to 75°C operation. The value of  $R_X$  may vary from 5.0 k $\Omega$  to 25 k $\Omega$  for -55 to +125°C operation.
- The value of  $C_X$  may vary from 0 to any necessary value available. If, however, the capacitor has leakages approaching 3.0  $\mu$ A or if stray capacitance from either terminal to ground is more than 50 pF, the timing equations may not represent the pulse width obtained.
- The output pulse with (t) is defined as follows:

$$t = 0.31 R_X C_X \left( 1 + \frac{1}{R_X} \right)$$

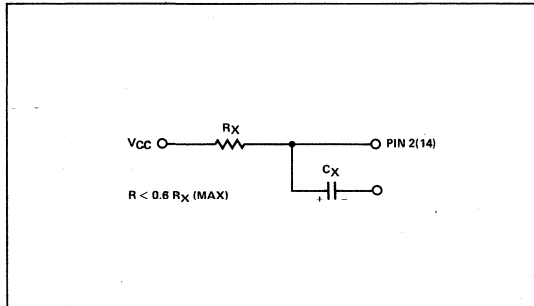
Where

$R_X$  is in k $\Omega$ ,  $C_X$  is in pF

t is in ns

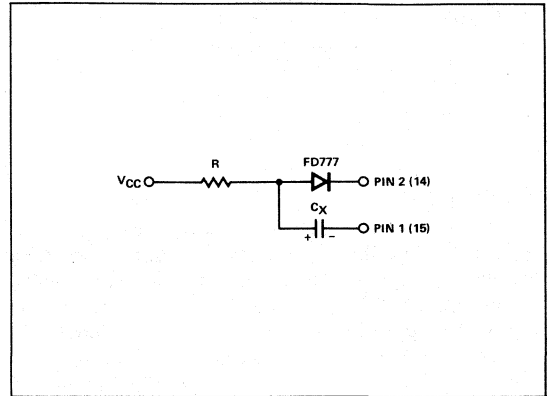
for  $C_X < 10^3$  pF, see Fig. 14

- If electrolytic type capacitors are to be used, the following three configurations are recommended:



**1. Use with low leakage capacitors:**

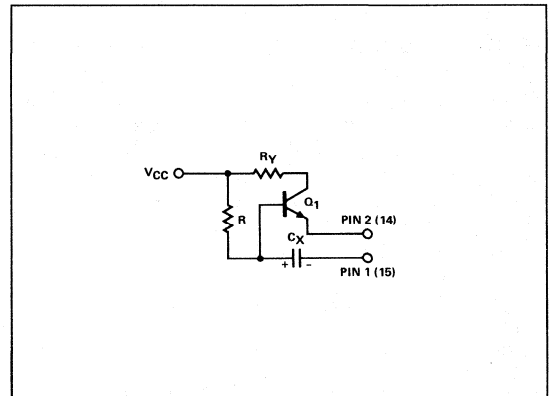
The normal RC configuration can be used predictably only if the forward capacitor leakage at 5.0 volts is less than 3 $\mu$ A, and the inverse capacitor leakage at 1.0 volt is less than 5 $\mu$ A over the operational temperature range.



**2. Use with high inverse leakage current electrolytic capacitors:**

The diode in this configuration prevents high inverse leakage currents through the capacitor by preventing an inverse voltage across the capacitor. The use of this configuration is not recommended with retriggerable operation.

$$t \approx 0.3 RC_X$$



**3. Use to obtain extended pulse widths:**

This configuration can be used to obtain extended pulse widths, because of the larger timing resistor allowed by beta multiplication. Electrolytics with high inverse leakage currents can be used.

$R < R_X (0.7) (h_{FE} Q_1)$  or  $< 2.5 M\Omega$  whichever is the lesser

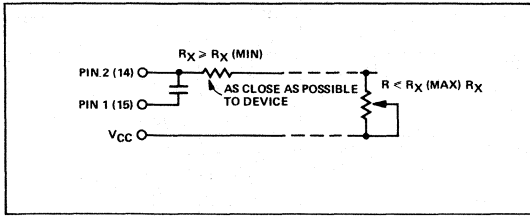
$R_X$  (min)  $< R_Y < R_X$  (max) ( $5 \leq R_Y \leq 10$  k $\Omega$  is recommended)

$Q_1$ : NPN silicon transistor with  $h_{FE}$  requirements of above equations, such as 2N5961 or 2N5962

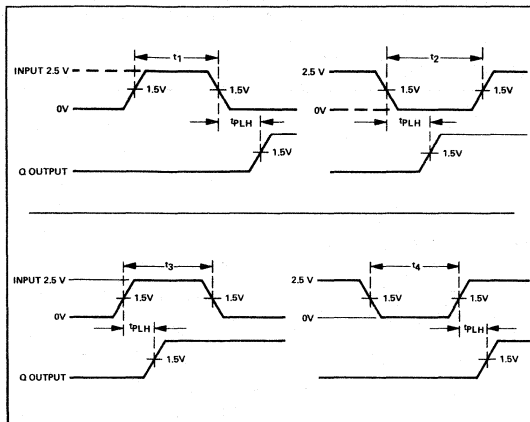
$$t \approx 0.3 RC_X$$

This configuration is not recommended with retriggerable operation.

- To obtain variable pulse width by remote trimming, the following circuit is recommended:

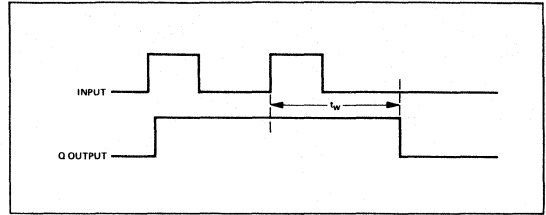


- Under any operating condition,  $C_X$  and  $R_X$  (min) must be kept as close to the circuit as possible to minimize stray capacitance and reduce noise pickup.
- Input Trigger Pulse Rules. See Triggering Truth Table, following pages.



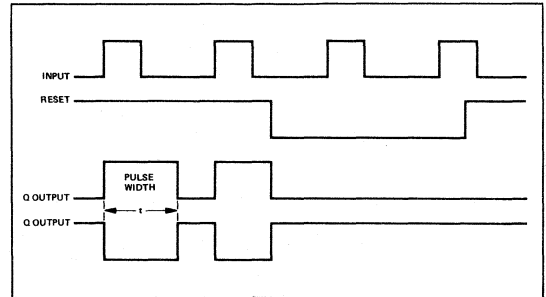
- The retriggerable pulse width is calculated as shown below:

$$t_w = t + t_{PLH} = 0.31 R_X C_X \left(1 + \frac{1}{R_X}\right) + t_{PLH}$$



The retrigger pulse width is equal to the pulse width ( $t$ ) plus a delay time. For pulse widths greater than 500 ns,  $t_w$  can be approximated as  $t$ . Retriggering will not occur if the retrigger pulse comes within  $\approx 0.3 C_X$  ns after the initial trigger pulse. (i.e., during the discharge cycle)

- Reset Operation—An overriding active LOW level is provided on each oneshot. By applying a LOW to the reset, any timing cycle can be terminated or any new cycle inhibited until the LOW reset input is removed. Trigger inputs will not produce spikes in the output when the reset is held LOW.



- $V_{CC}$  and Ground wiring should conform to good high frequency standards so that switching transients on  $V_{CC}$  and Ground leads do not cause interaction between one-shots. Use of a 0.01 to 0.1  $\mu F$  bypass capacitor between  $V_{CC}$  and Ground located near the 9602 is recommended.

TABLE I - ELECTRICAL CHARACTERISTICS  $T_A = -55^\circ C$  to  $125^\circ C$ ,  $V_{CC} = 5 V \pm 10\%$ .

SYMBOL	PARAMETER	LIMITS				UNITS	CONDITIONS (NOTE 1)	
		-55°C		+25°C				+125°C
		MIN	MAX	MIN	TYP			MAX
$V_{OH}$	Output HIGH Voltage	2.4		2.4	3.3	2.4	Volts	$V_{CC} = 4.5V$ , $I_{OH} = -0.96$ mA (Note 2)
$V_{OL}$	Output LOW Voltage		0.4		0.2	0.4	Volts	$V_{CC} = 4.5V$ , $I_{OL} = 9.92$ mA (Note 2) $V_{CC} = 5.5V$ , $I_{OL} = 12.8$ mA
$V_{IH}$	Input HIGH Voltage	2.0		1.7		1.5	Volts	Guaranteed Input HIGH Threshold Voltage
$V_{IL}$	Input LOW Voltage		0.85		0.90	0.85	Volts	Guaranteed Input LOW Threshold Voltage
$I_{IL}$	Input LOW Current	-1.6		-1.1	-1.6	-1.6	mA	$V_{CC} = 5.5V$ , $V_{IN} = 0.4V$
			-1.24		-0.97	-1.24	mA	$V_{CC} = 4.5V$ , $V_{IN} = 0.4V$
$I_{IH}$	Input HIGH Current			10	60	60	$\mu A$	$V_{CC} = 5.5V$ , $V_{IN} = 4.5V$

ELECTRICAL CHARACTERISTICS (Cont'd)

I <sub>SC</sub>	Short Circuit Current			-25			mA	V <sub>CC</sub> = 5.5V, V <sub>OUT</sub> = 1.0V (Note 2)
I <sub>PD</sub>	Quiescent Power Supply Drain	45	39	45	45		mA	V <sub>CC</sub> = 5.0V
t <sub>PLH</sub>	Negative Trigger Input to True Output		25	35			ns	V <sub>CC</sub> = 5.0V R <sub>X</sub> = 5.0 kΩ C <sub>X</sub> = 0, C <sub>L</sub> = 15pF
t <sub>PHL</sub>	Negative Trigger Input to Complement Output		29	43			ns	V <sub>CC</sub> = 5.0V R <sub>X</sub> = 5.0 kΩ C <sub>X</sub> = 0, C <sub>L</sub> = 15pF
t <sub>(min)</sub>	Minimum True Output Pulse Width		72	90			ns	V <sub>CC</sub> = 5.0V R <sub>X</sub> = 5.0 kΩ
	Minimum Complement Output Pulse Width		78	100			ns	C <sub>X</sub> = 0, C <sub>L</sub> = 15pF
t	Pulse Width		3.08	3.42	3.76		μs	V <sub>CC</sub> = 5.0V, R <sub>X</sub> = 10 kΩ, C <sub>X</sub> = 1000pF
C <sub>STRAY</sub>	Maximum Allowable Wiring Cap (Pins 2 and 14)	50		50			pF	Pins 2 and 15 to Ground
R <sub>X</sub>	Timing Resistor	5.0	25	5.0	25	5.0	25	kΩ

TABLE II - ELECTRICAL CHARACTERISTICS T<sub>A</sub> = 0°C to 75°C, V<sub>CC</sub> = 5 V ±5%.

SYMBOL	PARAMETER	LIMITS				UNITS	CONDITIONS (NOTE 1)	
		0°C		+25°C				+75°C
		MIN	MAX	MIN	TYP			MAX
V <sub>OH</sub>	Output HIGH Voltage	2.4		2.4	3.4	2.4	Volts	V <sub>CC</sub> = 4.75 V, I <sub>OH</sub> = -0.96mA (Note 2)
V <sub>OL</sub>	Output LOW Voltage	0.45		0.2	0.45	0.45	Volts	V <sub>CC</sub> = 4.75V, I <sub>OL</sub> = 11.3mA (Note 2) V <sub>CC</sub> = 5.25V, I <sub>OL</sub> = 12.8mA
V <sub>IH</sub>	Input HIGH Voltage	1.9		1.8		1.65	Volts	Guaranteed Input HIGH Threshold Voltage
V <sub>IL</sub>	Input LOW Voltage	0.85		0.85		0.85	Volts	Guaranteed Input LOW Threshold Voltage
I <sub>IL</sub>	Input LOW Current	-1.6		-10	-1.6	-1.6	mA	V <sub>CC</sub> = 5.25V, V <sub>IN</sub> = 0.45V
		-1.41			-1.41	-1.41	mA	V <sub>CC</sub> = 4.75V, V <sub>IN</sub> = 0.45V
I <sub>IH</sub>	Input HIGH Current			10	60	60	μA	V <sub>CC</sub> = 5.25V, V <sub>IN</sub> = 4.5V
I <sub>SC</sub>	Short Circuit Current					-35	mA	V <sub>CC</sub> = 5.25V, V <sub>OUT</sub> = 1.0V (Note 2)
I <sub>PD</sub>	Quiescent Power Supply Drain	52		39	50	52	mA	V <sub>CC</sub> = 5.0V, Ground Pins 1 and 2
t <sub>PLH</sub>	Negative Trigger Input to True Output			25	40		ns	V <sub>CC</sub> = 5.0V R <sub>X</sub> = 5.0 kΩ C <sub>X</sub> = 0, C <sub>L</sub> = 15pF
t <sub>PHL</sub>	Negative Trigger Input to Complement Output			29	48		ns	V <sub>CC</sub> = 5.0V R <sub>X</sub> = 5.0 kΩ C <sub>X</sub> = 0, C <sub>L</sub> = 15pF
t <sub>(min)</sub>	Minimum True Output Pulse Width			72	100		ns	V <sub>CC</sub> = 5.0V R <sub>X</sub> = 5.0 kΩ
	Minimum Complement Output Pulse Width			78	110		ns	C <sub>X</sub> = 0, C <sub>L</sub> = 15pF



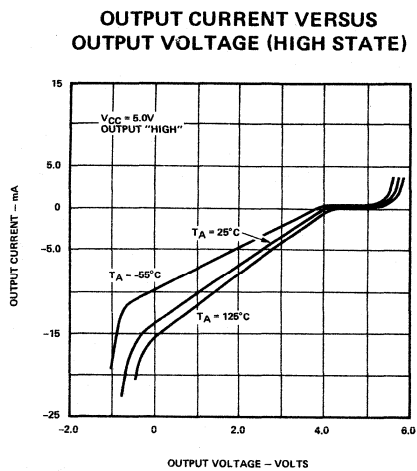
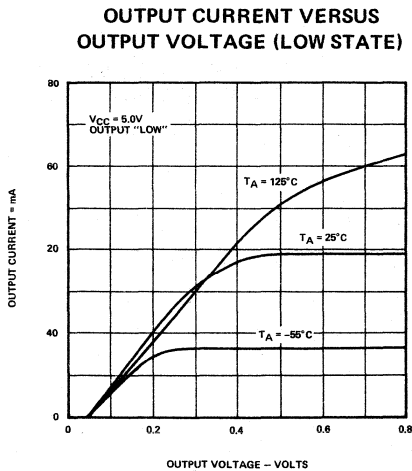
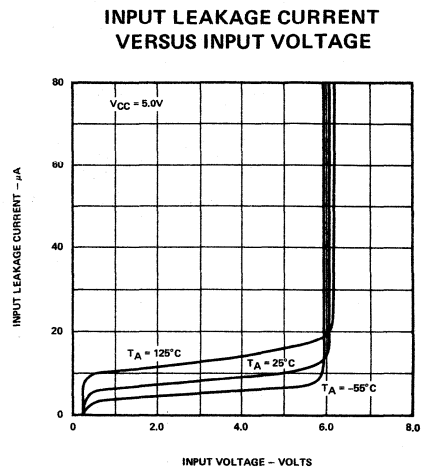
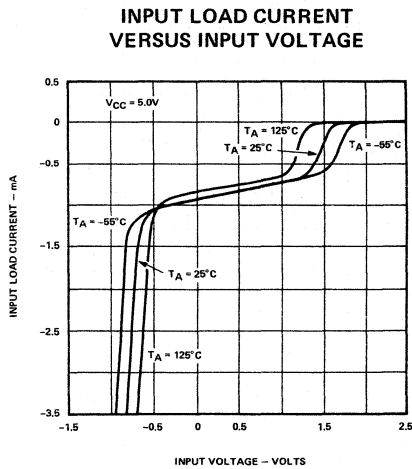
ELECTRICAL CHARACTERISTICS (Cont'd)

t	Pulse Width		3.08	3.42	3.76		$\mu\text{s}$	$V_{CC} = 5.0\text{V}$ , $R_X = 10\text{ k}\Omega$ , $C_X = 1000\text{pF}$ Pins 2 and 14 to Ground
C <sub>STRAY</sub>	Maximum Allowable Wiring Cap, (Pins 2 and 14)	50		50		50	pF	
R <sub>X</sub>	Timing Resistor	5.0	50	5.0	50	5.0	50	k $\Omega$

NOTES:

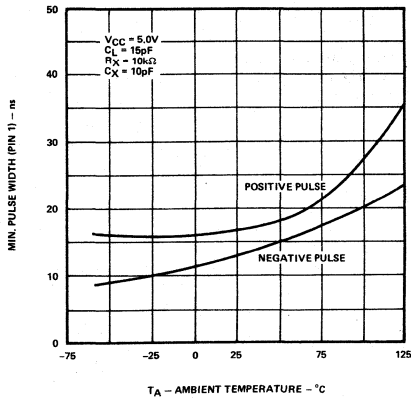
1. Unless otherwise noted, 10 k $\Omega$  resistor placed between Pin 2 (14) and V<sub>CC</sub>, for all tests. (R<sub>X</sub>)
2. Ground Pin 1 (15) for V<sub>OL</sub> on Pin 7 (9), or for V<sub>OH</sub> on Pin 6 (10), or for I<sub>SC</sub> on Pin 6 (10); also, apply momentary ground to Pin 4 (12). Open Pin 1 (15) for V<sub>OL</sub> on Pin 6 (10), or for V<sub>OH</sub> on Pin 7 (9), or for I<sub>SC</sub> on Pin 7 (9).

CHARACTERISTIC CURVES

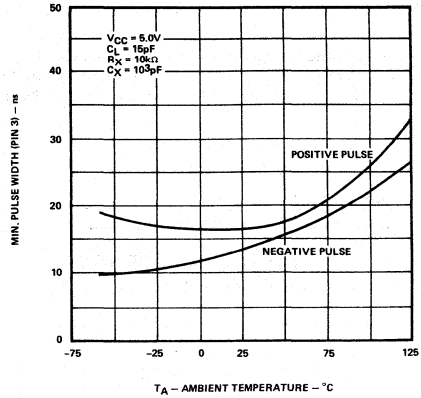


CHARACTERISTIC CURVES ( Cont'd)

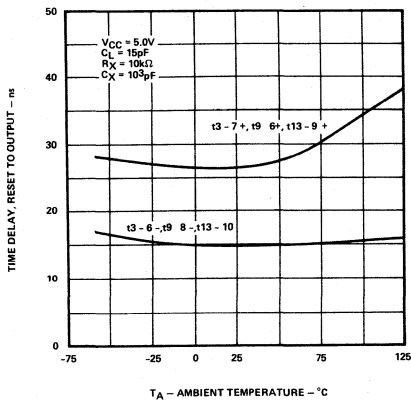
**MINIMUM PULSE WIDTH TO TRIGGER VERSUS AMBIENT TEMPERATURE (POSITIVE EDGE TRIGGER INPUT)**



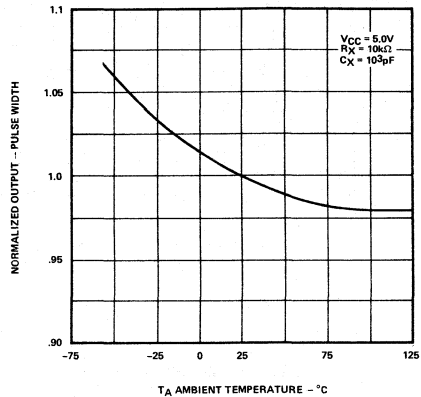
**MINIMUM PULSE WIDTH TO TRIGGER VERSUS AMBIENT TEMPERATURE (NEGATIVE EDGE TRIGGER INPUT)**



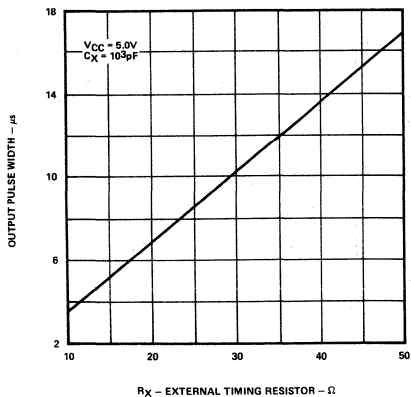
**MINIMUM TIME DELAY, RESET TO OUTPUT VERSUS AMBIENT TEMPERATURE**



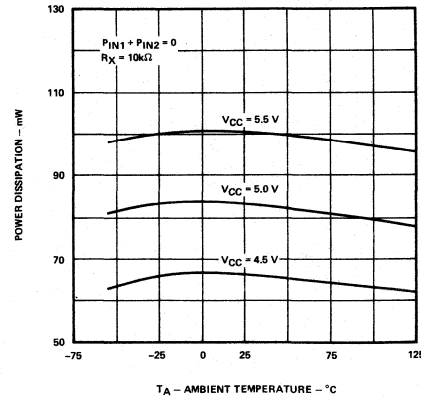
**NORMALIZED OUTPUT PULSE WIDTH VERSUS AMBIENT TEMPERATURE**



**PULSE WIDTH VERSUS TIMING RESISTOR**

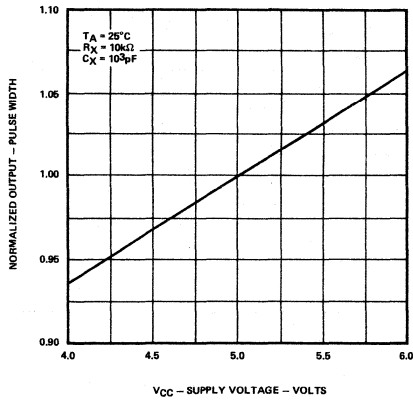


**POWER DISSIPATION VERSUS AMBIENT TEMPERATURE**

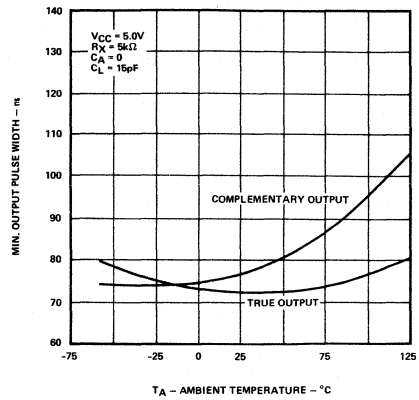


CHARACTERISTIC CURVES ( Cont'd)

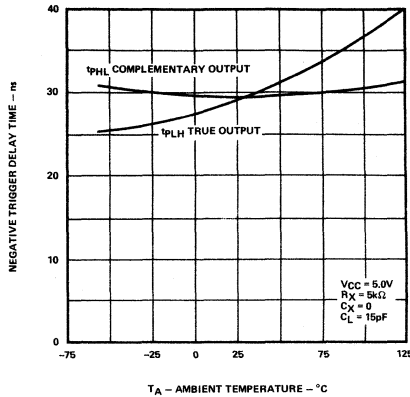
**NORMALIZED OUTPUT PULSE WIDTH VERSUS SUPPLY VOLTAGE**



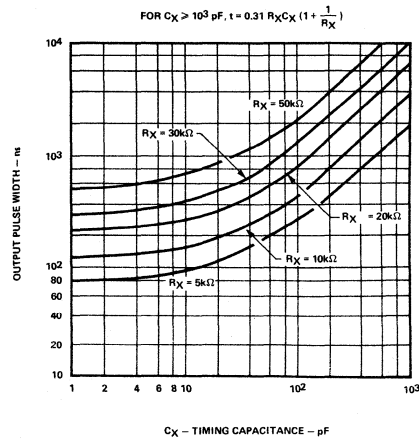
**MINIMUM OUTPUT PULSE WIDTH VERSUS AMBIENT TEMPERATURE**



**NEGATIVE TRIGGER DELAY TIME VERSUS AMBIENT TEMPERATURE**



**OUTPUT PULSE WIDTH VERSUS TIMING RESISTANCE AND CAPACITANCE FOR  $C_X < 10^3$  pF**



TRIGGERING TRUTH TABLE

PIN NUMBERS			OPERATION
5 (11)	4 (12)	3 (13)	
H → L	L	H	Trigger
H	H → L	H	Trigger
X	X	L	Trigger

H = HIGH Voltage Level  $\geq V_{IH}$

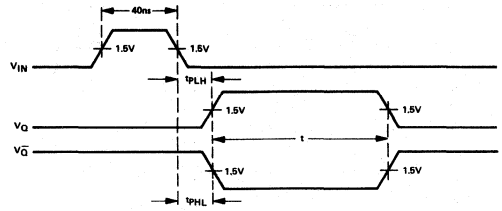
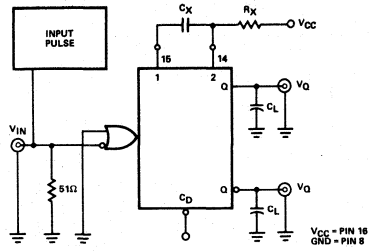
L = LOW Voltage Level  $\leq V_{IL}$

X = Don't Care

H→L = HIGH to LOW Voltage Level Transition

L→H = LOW to HIGH Voltage Level Transition

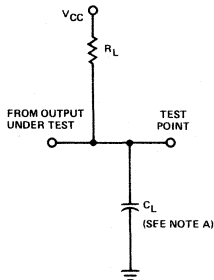
SWITCHING CIRCUITS AND WAVEFORM



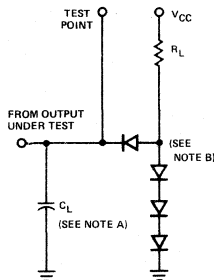
# 54/74S Typical A.C. Loads And Waveforms

## PARAMETER MEASUREMENT INFORMATION

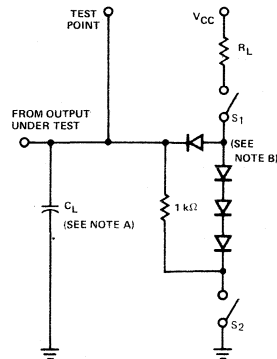
**LOAD CIRCUIT FOR OPEN-COLLECTOR OUTPUTS**



**LOAD CIRCUIT FOR BI-STATE TOTEM-POLE OUTPUTS**



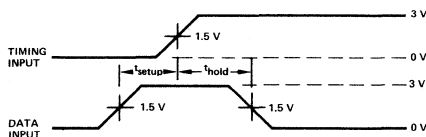
**LOAD CIRCUIT FOR TRI-STATE OUTPUTS**



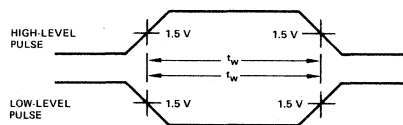
NOTES: A.  $C_L$  includes probe and jig capacitance.  
B. All diodes are 1N3064.

## TYPICAL AC WAVEFORMS

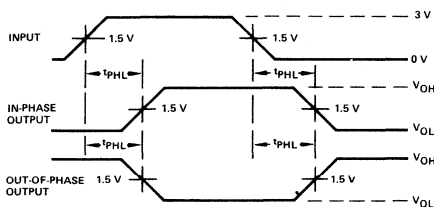
**VOLTAGE WAVEFORMS SETUP AND HOLD TIMES**



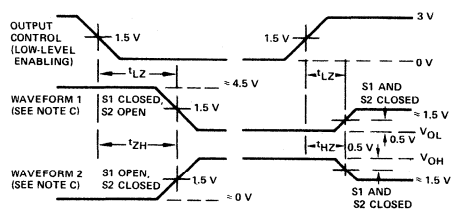
**VOLTAGE WAVEFORMS PULSE WIDTHS**



**VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES**



**VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, TRI-STATE OUTPUTS**



NOTES: C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
D. In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily.  
E. All input pulses are supplied by generators having the following characteristics:  $t_r \leq 2.5$  ns,  $t_f \leq 2.5$  ns,  $PRR \leq 1$  MHz, and  $Z_{out} \approx 50 \Omega$ .



**Signetics**

MSI/TTL  
8000 PRODUCT  
SPECIFICATIONS

**3**





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## 8200 MSI Functional Index

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**82S OPTIMIZED SCHOTTKY MSI (Continued)**

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## INTRODUCTION AND ORDERING INFORMATION

### INTRODUCTION

The 8200 Series MSI, 82S Schottky MSI and 8T interface circuits are described in this section. These devices are directly compatible with other TTL circuits such as the bipolar memories covered in Section 4 and the 54/74 series described in Section 2.

Other 8000 Series circuits such as gates, binaries and several interface elements are described in a separate publication, that may be obtained from your nearest Signetics representative.

The electrical specifications given for the IC's in this section are designed to serve as an exact guide for procurement documents. Detailed test conditions and test limits are given for each integrated circuit. Whenever possible, worst case limits for the electrical parameters have been provided.

Ordering information for the circuits described in this section can be found below. This information should be reviewed in conjunction with detailed package descriptions given in Section 8 where physical dimensions as well as thermal impedance data are given.

Reliability information that details production screens, acceptance tests and qualification tests is given in Section 8 as well. The users attention is also directed to the optional high reliability programs described in Section 8. These are the Signetics SUPR DIP Program for plastic packages and the Signetics SURE 883 program.

Usage information may be found in the Signetics Applications Handbook also available. Additional applications information may be obtained from the nearest Signetics representative or local Signetics field applications engineer. The user may also find the general systems design considerations helpful which are given on pages 3-2 through 3-7.

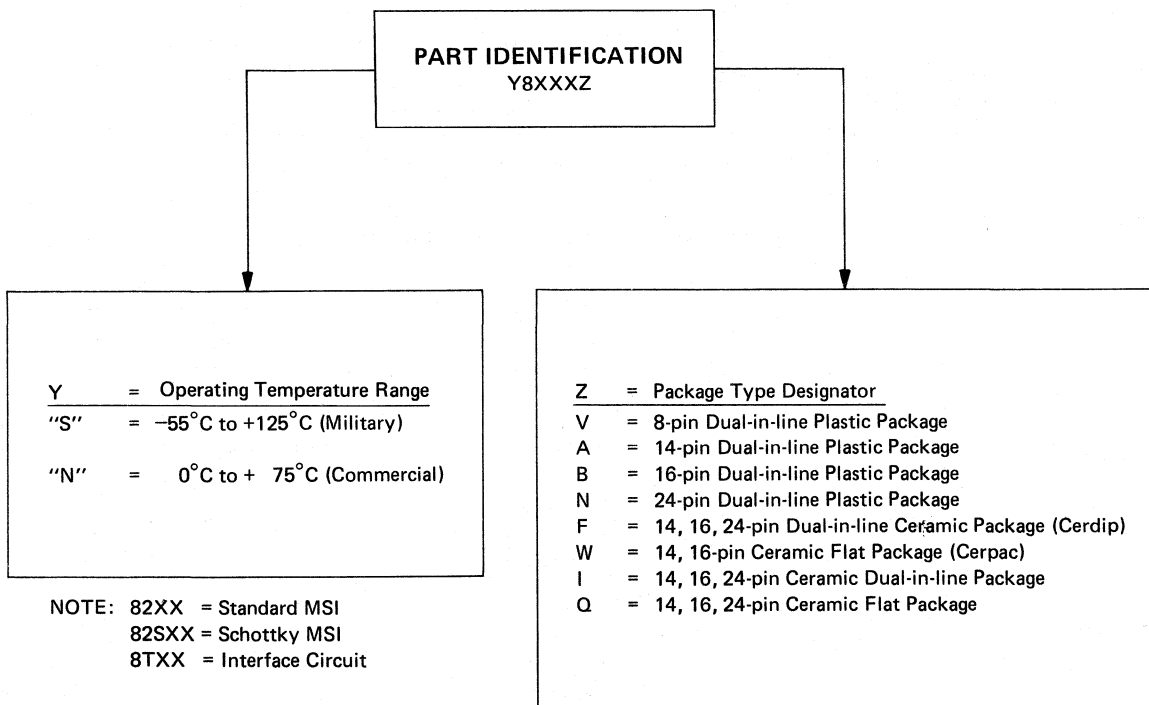
### ORDERING INFORMATION

Unless otherwise specified all devices are available in the "S" and "N" temperature ranges:

"S" =  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$

"N" =  $0^{\circ}\text{C}$  to  $+75^{\circ}\text{C}$

The package type designators below, in conjunction with detailed package information given in section 8, may be used for procurement purposes.



## SYSTEMS DESIGN CONSIDERATIONS

### ABSOLUTE MAXIMUM RATINGS

Over Operating Free-Air Temperature Range (unless otherwise noted)

The absolute maximum ratings constitute limiting values above which serviceability of the device may be impaired. Provisions should be made in system design and testing to limit voltages in accordance with Table 1. These ratings apply to both 82XX and 8TXX MSI devices unless otherwise specified.

TABLE 1	
Input Voltage	+5.5V
Output Voltage	+7.0V
V <sub>CC</sub> (Note 2)	+7.0V
Storage Temperature Range	
A, B, N packages	-65°C to +175°C
F, I, Q, W packages	-65°C to +200°C
NOTES:	
1. All devices must be derated at elevated temperatures based on maximum allowable junction temperature. (See maximum storage temperature above and the thermal resistance of the package, given in section 8).	
2. Operating V <sub>CC</sub> for the 8200 Series is specified at +5V ± 5%. None of the Signetics MSI elements will be damaged by supply voltages of 7 volts or less; however, in some of the more complex functions, power dissipation at such voltages could become excessive. It is recommended therefore, that such over-voltages be limited to a maximum of 1 second duration.	

## SYSTEMS DESIGN CONSIDERATIONS

### DC Fan-Out and Noise Margin

Because of the growing complexity of new MSI and memory products, loading and noise margin tables are not

included in this section. The numbers are easily generated for individual cases as shown below. The lower of the two numbers is the DC fan-out.

$$\text{DC FAN OUT ("0" Output Condition)} = \frac{\text{"0" maximum output current of driving element}}{\text{"0" maximum input current requirement of driven element}}$$

$$\text{DC FAN OUT ("1" Output Condition)} = \frac{\text{"1" maximum output current of driving element}}{\text{"1" maximum input current requirement of driven element}}$$

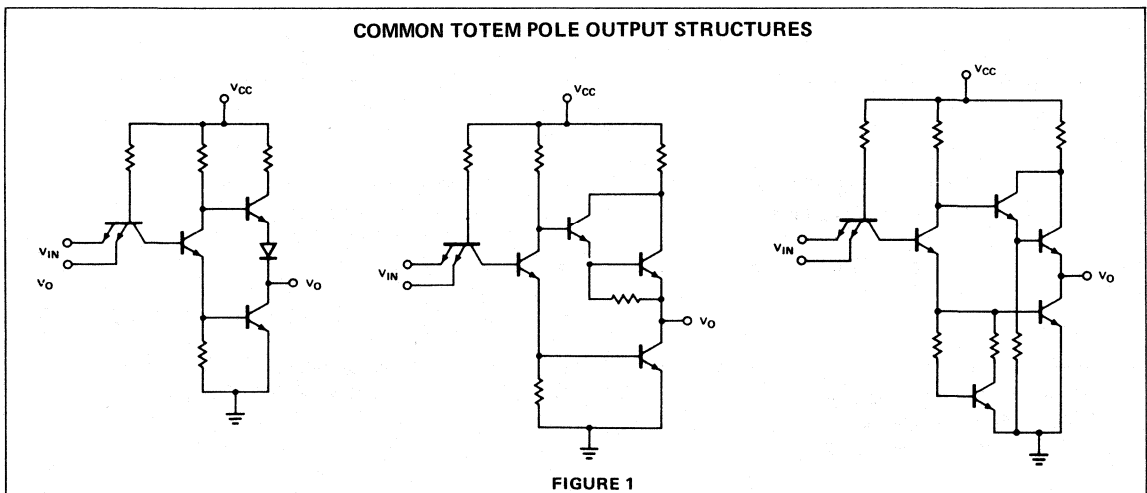
DC Noise Margin ("0" state) is obtained by subtracting the maximum "0" level output voltage for the driving gate from the minimum "0" threshold for the driven gate.

DC Noise Margin ("1" state) is obtained by subtracting the maximum "1" level input threshold of the driven gate from the minimum "1" output voltage level of the driving gate.

### OUTPUT STRUCTURES

Certain guidelines should be observed to ensure optimum system performance. Systems incorporating TTL elements such as gates, binaries and MSI circuits have inherent V<sub>CC</sub> and GROUND transients attributable to the current spike produced by "totem pole" output structures.

Figure 1 shows totem pole structures commonly used in MSI designs as output buffers to increase fan-out and provide adequate switching speeds.



**DECOUPLING MSI**

The current spike produced by the totem pole output structure during switching transitions can cause MSI subsystems to malfunction if  $V_{CC}$  is not adequately decoupled to GROUND. With the large number of SSI and MSI devices available it is almost impossible to establish a general rule for decoupling. When in doubt, a capacitor of 2000pF or more, for each totem pole structure should be connected from  $V_{CC}$  to GROUND. The non-inductive capacitor (ceramic disc, tantalum slug, etc.) should be mounted with leads as short as possible and should be placed in close proximity to the MSI package to minimize lead length inductance. A properly designed printed circuit board should have the total required capacitance evenly distributed throughout the board. Example: A printed circuit board contains 25 packages averaging four totem pole structures per package. The total capacitance required is 25 packages  $\times$  4 totem pole structures  $\times$  2000pF or 0.2 $\mu$ F ceramic disc capacitors evenly distributed, satisfy the  $V_{CC}$  to GROUND decoupling requirements.

**POWER SUPPLY AND GROUND DISTRIBUTION SYSTEMS**

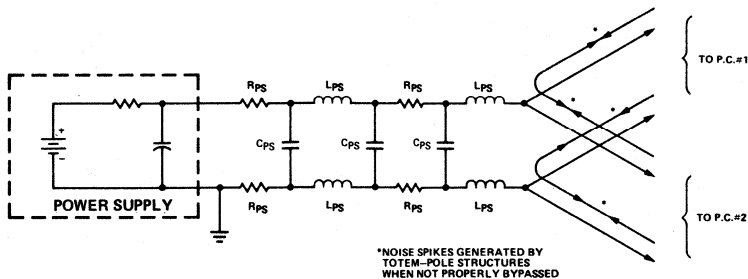
High-frequency distribution techniques should be used for  $V_{CC}$  and GROUND. These techniques should include a

large ground plane to minimize DC offsets and to provide an extremely low impedance path to reduce transient voltage signals on the printed circuit board. The power supply should be +5V  $\pm$ 5% with R-F (1GHz) bypassing. Catastrophic damage can occur if  $V_{CC}$  is not properly regulated.

Power distributed from the main supply must, by necessity, come through a path which displays finite resistance ( $R_{ps}$ ), inductance ( $L_{ps}$ ) and capacitance ( $C_{ps}$ ), as illustrated in Figure 2. The resistive component of the power lines is

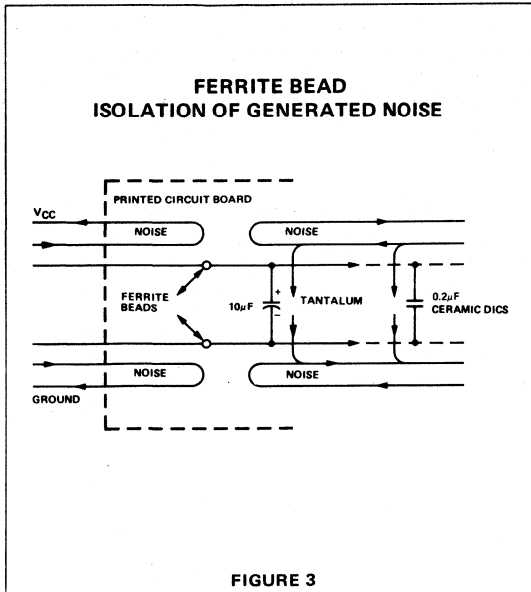
small, producing very little DC voltage drop at the  $V_{CC}$  and GROUND inputs to the printed circuit board. However, the inductance in the power lines can cause the noise generated by current spiking to be transmitted throughout the system on the  $V_{CC}$  and GROUND lines. If the printed circuit boards are adequately decoupled, the power line noise will be reduced significantly. In order to repel power line noise transmitted to a printed circuit board, ferrite beads may be placed on the incoming  $V_{CC}$  and GROUND lines as shown in Figure 3. A 10 $\mu$ f tantalum capacitor, per 25 packages, connected from  $V_{CC}$  to GROUND should be placed on the printed circuit board in the position shown. In conjunction with the distributed ceramic disc capacitors, this approach will prevent most system malfunctions attributable to internally generated noise.

**POWER CHARACTERISTIC IMPEDANCE**



**FIGURE 2**

## SYSTEMS DESIGN CONSIDERATIONS



### ISOLATION DIODES

NEVER REVERSE THE  $V_{CC}$  AND GROUND POTENTIALS. Catastrophic failure can occur if more than 100mA is conducted through a forward biased substrate (isolation) diode.

### DISPOSITION OF UNUSED INPUTS

Electrically open inputs degrade AC noise immunity as well as the switching speed of an MSI circuit. To optimize performance, each input must be connected to a low impedance source. Depending on their logical activating level, unused inputs should be tied to  $V_{CC}$ , GROUND or a driving source. When paralleling an unused input with a driven input of the same multiple emitter transistor (MET), care should be taken to remain within the "1" level fan-out specifications for the driving source. The AND or NAND structures do not affect the "0" level fan-out of the driving source. When an unused input of an OR or NOR structure is commoned with a driven input, both the "1" and "0" level fan-out of the driving source are affected.

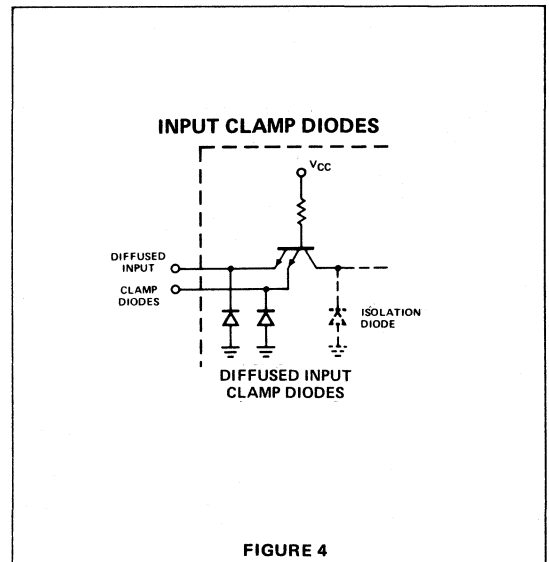
If fan-out of the driving source will be exceeded or if there is no convenient connection to an appropriate driven input, a second method of avoiding open inputs is useful. Inputs which activate on "0" (AND and NAND) may be tied directly to  $V_{CC}$  or tied to  $V_{CC}$  through a current limiting resistor of 1 K $\Omega$  or more.

The current limiting resistor is required if power supply transients can exceed 5.5V for longer than 1 $\mu$ sec; since the power dissipated in the emitter junction under these conditions can destroy the junction.

More than one unused input can be tied to  $V_{CC}$  through a single resistor.

### INPUT CLAMP DIODES

MSI circuits contain input clamp diodes as shown in Figure 4. At the input, these diodes limit negative excursions which exceed -1V by providing a low impedance current source from GROUND through the forward biased diode clamp. The clamps are designed to minimize ringing which may result from interconnect wires in excess of six inches in length.



### SIGNAL PROCESSING

The rise and fall times of all incoming data signals should be less than 200ns. The amplitude of incoming data signals should be 2.4V or greater. Figure 5 shows the transfer characteristic of the classic TTL gate. In the input threshold region, from point one to point two, the gate has approximately 25dB of gain. In this region, any discontinuity of the input waveform will be amplified more than 10 times at the output of the gate.



TTL TRANSFER CHARACTERISTIC

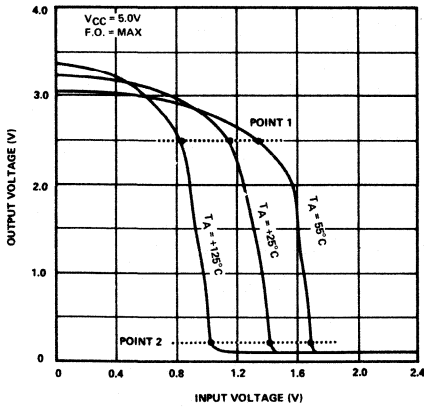


FIGURE 5

Should the input voltage remain in the threshold region (approximately 200mV wide) for more than 15ns, a typical TTL gate tends to oscillate as shown in Figure 6. The equivalent circuit in Figure 7 illustrates the potential oscillatory feed-back paths. The primary contributor to oscillation is the changing power supply voltage with the chip, caused by the current spiking which occurs during switching transitions. Since output voltage is directly proportional to  $V_{CC}$  and threshold voltage tends also to drop with lower supply voltage, the net effect is a positive feedback loop from output to input.

POTENTIAL OSCILLATORY FEEDBACK PATHS

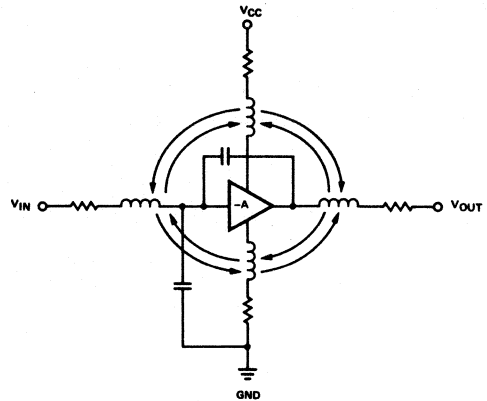


FIGURE 7

TYPICAL TTL GATE OSCILLATION WITH SLOW INPUT TRANSITIONS

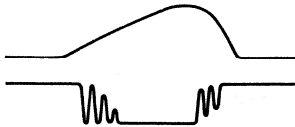


FIGURE 6

WIRED-AND APPLICATIONS OF OPEN-COLLECTOR MSI

Open-collector MSI, when supplied with a proper load resistor ( $R_L$ ) can be paralleled with other similar MSI or open collector TTL gates to perform the WIRED-AND function, and simultaneously, will drive several TTL loads. For any of these conditions an appropriate load resistor value must be determined for the desired circuit configuration. The user may choose a load resistor that must be between the following limits: A maximum resistor value must be determined which will ensure that sufficient load current to the TTL loads to be driven, as well as leakage current to the paralleled outputs, is available during the logical "1" state at the output. A minimum resistor value must be determined which will ensure that current through this resistor and sink current from the TTL loads will not cause the output voltage to rise above the logical "0" level even if one of the paralleled outputs is sinking all the current.

## SYSTEMS DESIGN CONSIDERATIONS

### LOGICAL "1" (off level) CALCULATIONS FOR $R_L$ MAX

The maximum value of load resistance ( $R_L$  MAX) is determined by the maximum voltage drop across  $R_L$  caused by the total leakage current which will still ensure a minimum logical "1" at the common collector node. As shown in Figure 8:

$$\text{Total leakage current } I(1)_{\text{total}} = n I(1)_{\text{off}} + m I(1)_{\text{in}}$$

$n$  = Number of commoned collectors (driving gates)

$m$  = Number of fan-outs (driven gates)

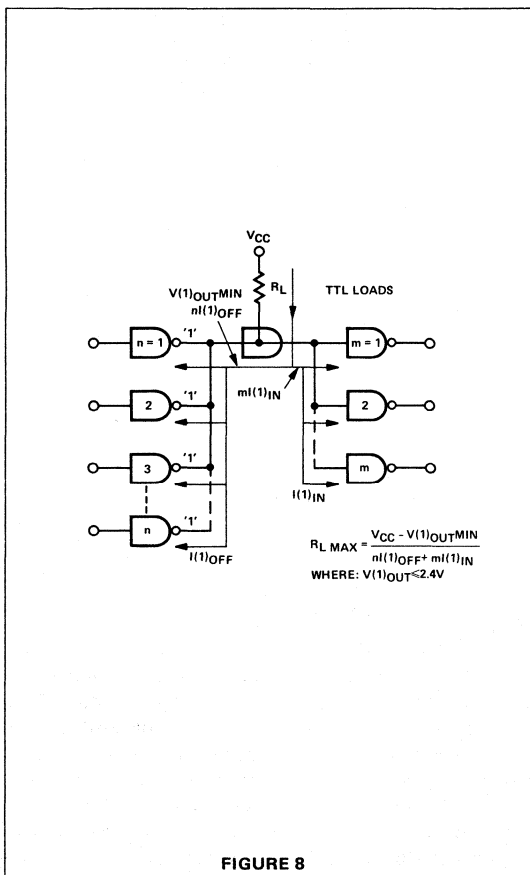


FIGURE 8

### LOGICAL "0" (on level) CALCULATIONS FOR $R_L$ MIN

The minimum value of load resistance ( $R_L$  MIN) is determined from the worst case maximum logical "0" state in which only one element is sinking current. This condition is illustrated in Figure 9:

3-6

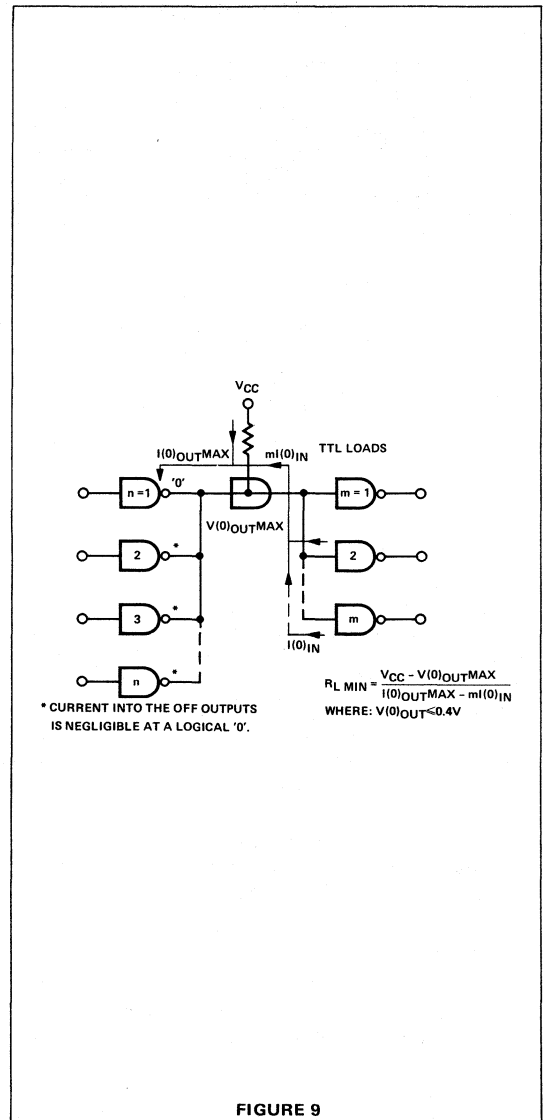


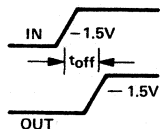
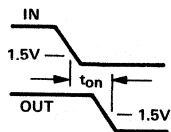
FIGURE 9

### PROPAGATION DELAY

Propagation delay for the 8000 Series elements is specified in terms of  $t_{\text{on}}$  and  $t_{\text{off}}$  switching times which provides a figure of merit by which comparison can be made with similar products. The guaranteed delay times given in the electrical characteristics section take into consideration the logical "1" and logical "0" input current and load capacitance as shown in the AC test figures. Inverting and non-inverting paths are measured as shown in Figure 10.

PROPAGATION DELAY WAVEFORMS

NON-INVERTING PATHS



INVERTING PATHS

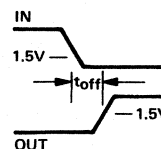
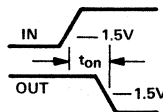


FIGURE 10

SIGNETICS 8200/82S APPLICATIONS NOTES

Detailed applications literature for the 8200/82S MSI circuits is published in the Signetics Applications Handbook.

8200/01/02/03	I/O Buffer Registers (10 Bits and Dual 5 Bits)
8230/31/32	8-Input Digital Multiplexers
82S30/S31/S32	
8233/34/35	2-Input 4-Bit Multiplexers
8266/67	
82S33/S34	
8241/42	Quad Exclusive OR/Quad Exclusive NOR
82S41/S42	
8243	8-Bit Position Scaler
8250/51/52	Octal/Decimal Decoders
82S51/S52	
8260/61	Arithmetic Logic Element
8262	9-Bit Parity Generator Checker
82S62	
8268	Gated Full Adder
8270/71	4-Bit Shift Registers
82S70/S71	
8275	Quad Latch
8276	8-Bit Serial Register
82S82/82S83	BCD Arithmetic Unit/BCD Adder
8280/81/88	
8290/91/92/93	Presetable 4-Bit Counters/Storage Elements (Binary, BCD, Divide-by-12)
82S90/82S91	
8284/85	Synchronous Up/Down Counters

### DESCRIPTION

The 8200/8201/8202/8203 MSI Buffer Registers are arrays of ten clocked "D" flip-flops especially suited for parallel-in parallel-out register applications. They are also suitable for general purpose applications as parallel-in serial-out, serial-in parallel-out registers.

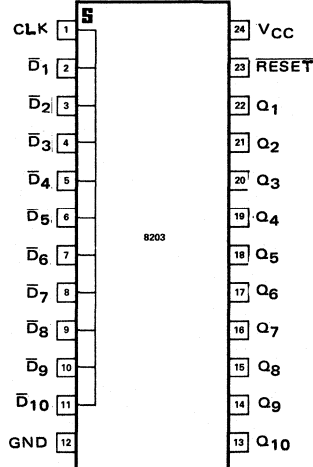
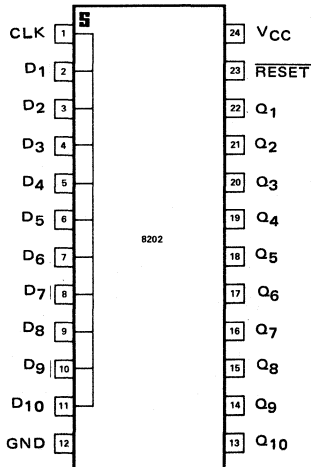
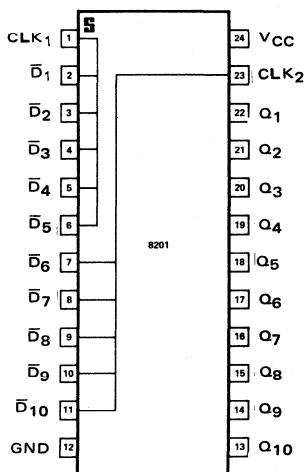
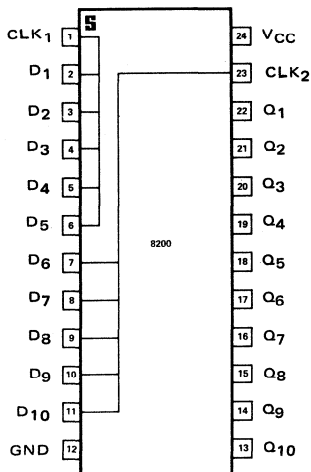
The flip-flops are arranged as dual 5 arrays, (8200 & 8201) and single 10 arrays with reset, (8202 & 8203). The true output of each bit is made available to the user.

The 8200 and 8202 feature true "D" inputs. The logic state presented at these "D" inputs will appear at the Q outputs after a negative transition of the clock.

The 8201 and 8203 feature complementing "D" inputs ("D-bar"). The logic state presented at these "D-bar" inputs will invert and appear at the Q outputs after a negative going transition of the clock. This complementing input feature ("D-bar") permits the use of standard AND-OR-INVERT gates to achieve the AND-OR function without additional gate delays.

### PIN CONFIGURATIONS (Top View)

#### N,F,Q PACKAGES



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	D <sub>n</sub> 8200 8202	$\overline{D}_n$ 8201 8203	CLOCK	$\overline{RESET}$ 8202 8203	OUTPUTS	
"1" Output Voltage	2.6	3.5		V	2.0V	0.8V	Pulse		- 800μA	6
"0" Output Voltage			0.4	V	0.8V	2.0V	Pulse		9.6mA	7
"0" Input Current										
D <sub>n</sub> (8200, 8202)	-0.1		-1.6	mA	0.4V					
D <sub>n</sub> (8201, 8203)	-0.1		-1.6	mA		0.4V				
Clock	-0.1		-1.6	mA			0.4V			
Reset (8202, 8203)	-0.1		-1.6	mA				0.4V		
"1" Input Current										
D <sub>n</sub> (8200, 8202)			40	μA	4.5V					
D <sub>n</sub> (8201, 8203)			40	μA		4.5V				
Clock			40	μA			4.5V			
Reset (8202, 8203)			40	μA				4.5V		
Input Voltage Rating (All inputs)	5.5			V	10mA	10mA	10mA	10mA		
Power/Current Consumption		409/77.7	580/110	mW/mA	0V	0V	0V			11,13

T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

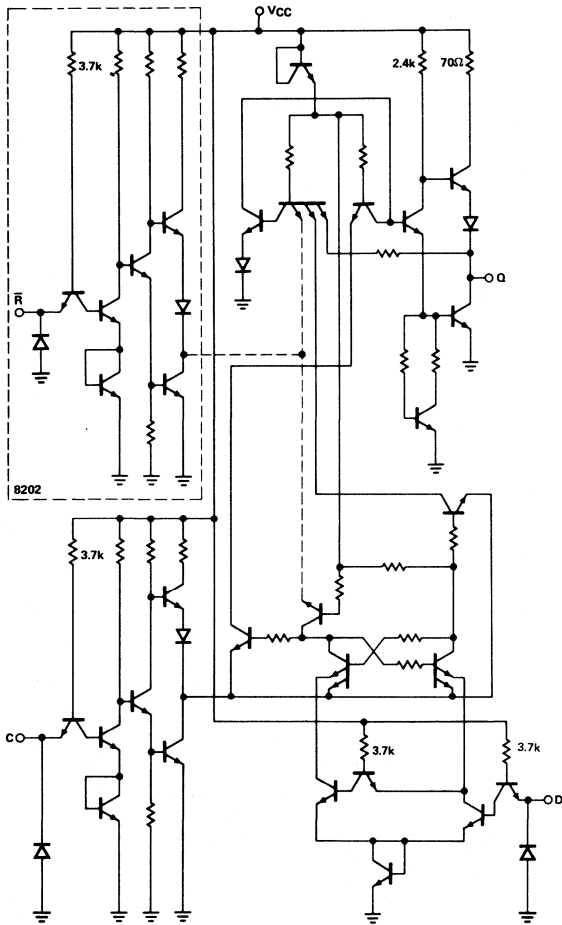
CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Propagation Delay						
t <sub>on</sub> Clock to Q		30	45	ns		8
t <sub>off</sub> Clock to Q		25	40	ns		8
t <sub>on</sub> Reset to Q		30	45	ns		8
Set Up Time		6	15	ns		10
Hold Time		0	5	ns		12
Minimum Clock Pulse Width		12	17	ns		
Transfer Rate		35		MHz		8
Output Short Circuit Current	-20		-70	mA		9, 13

**NOTES**

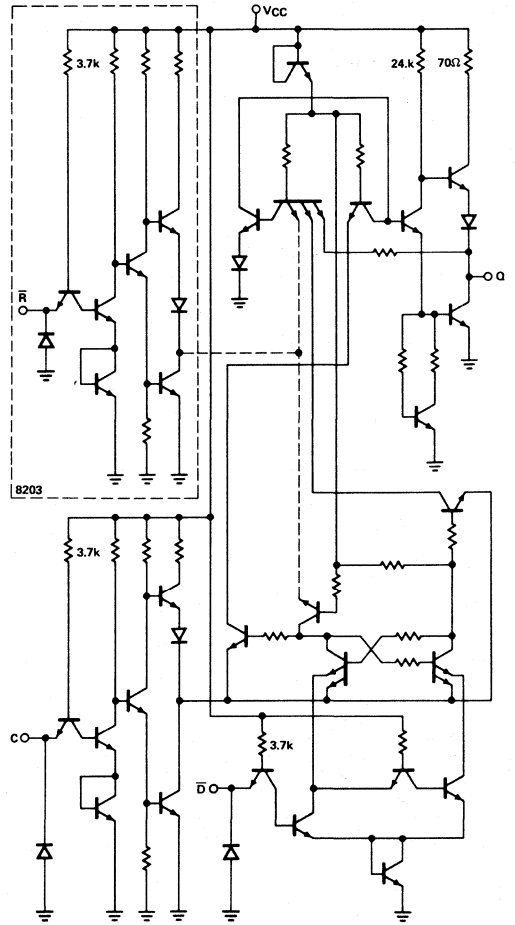
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are tied to V<sub>CC</sub>.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figure.
- Not more than one output should be shorted at a time.
- Set Up Time defined as data presence before clock.
- Outputs are in the low state for this test.
- Hold time defined as data presence after clock.
- V<sub>CC</sub> = 5.25 volts.

**SCHEMATIC DIAGRAMS**

**DUAL 5-BIT BUFFER REGISTER 8200  
SINGLE 10-BIT BUFFER REGISTER 8202**

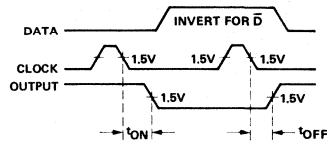
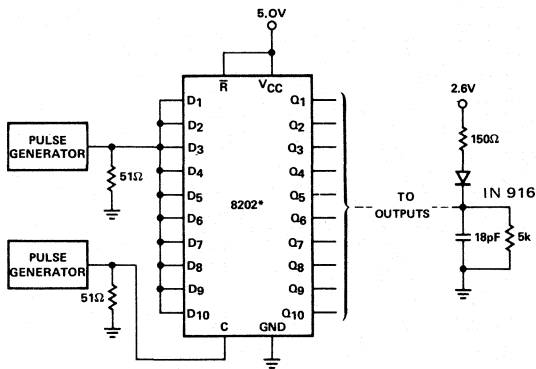


**DUAL 5-BIT BUFFER REGISTER  
INVERTED INPUTS 8201  
SINGLE 10-BIT BUFFER REGISTER  
INVERTED INPUTS 8203**



AC TEST FIGURES AND WAVEFORMS

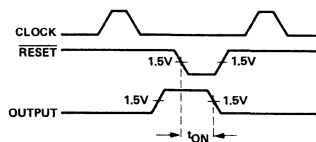
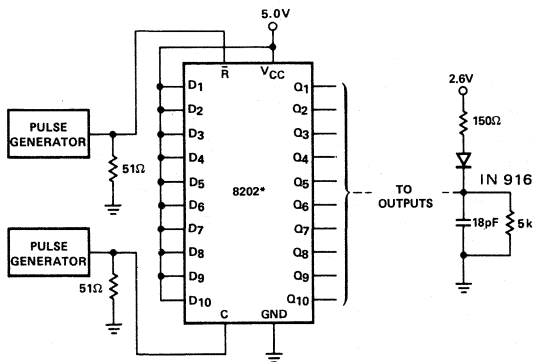
$t_{pd}$  FROM CLOCK TO Q



INPUT PULSE:  
 Data = P.R.R. = 7.5 MHz  
 Clock = P.R.R. = 15 MHz  
 PW = 17 ns (at 50% point)  
 $t_r = t_f = 5$  ns Max.  
 Amplitude = 2.6V.

\* Refer to the Pin-Outs for the 8200/01/03 AC Testing.

$t_{on}$  FROM RESET TO Q

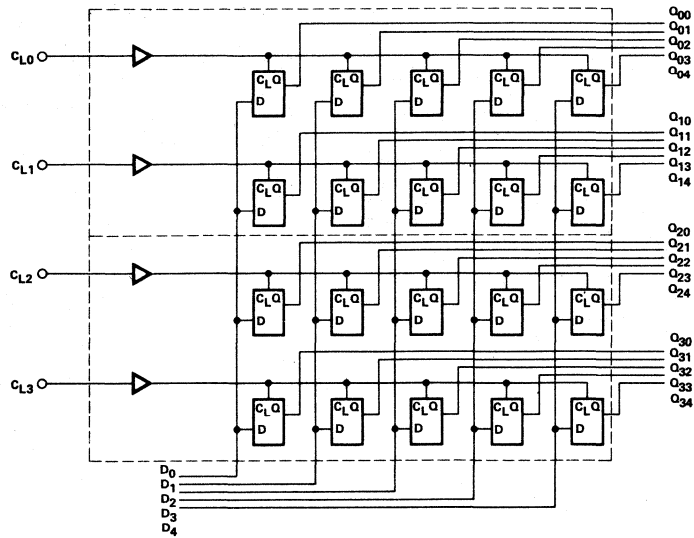


INPUT PULSE:  
 Amplitude = 2.6V  
 Clock: P.R.R. = 5 MHz  
 Reset: P.R.R. = 5 MHz  
 PW = 30 ns (at 50% point)  
 $t_r = t_f = 5$  ns

\* Refer to the Pin-Outs for the 8200/01/02/03 AC Testing.

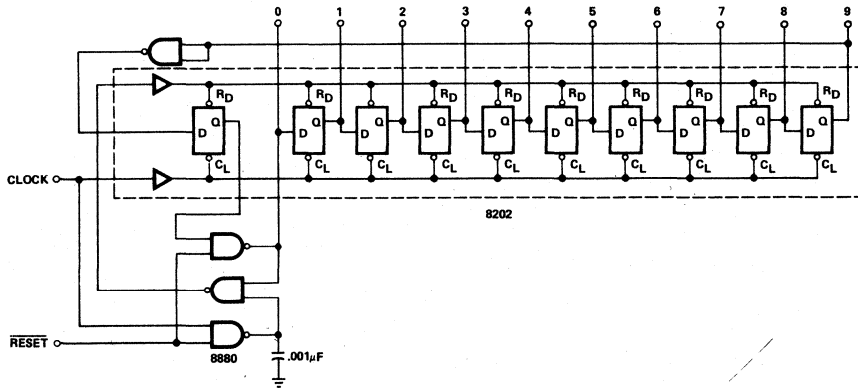
TYPICAL APPLICATIONS

20 BIT (4 WORDS X 5 BITS EACH) MEMORY CELL



Total Package Count = 2-8200's

ONE OUT OF TEN - COUNTER/DISPLAY (SELF-CORRECTING)

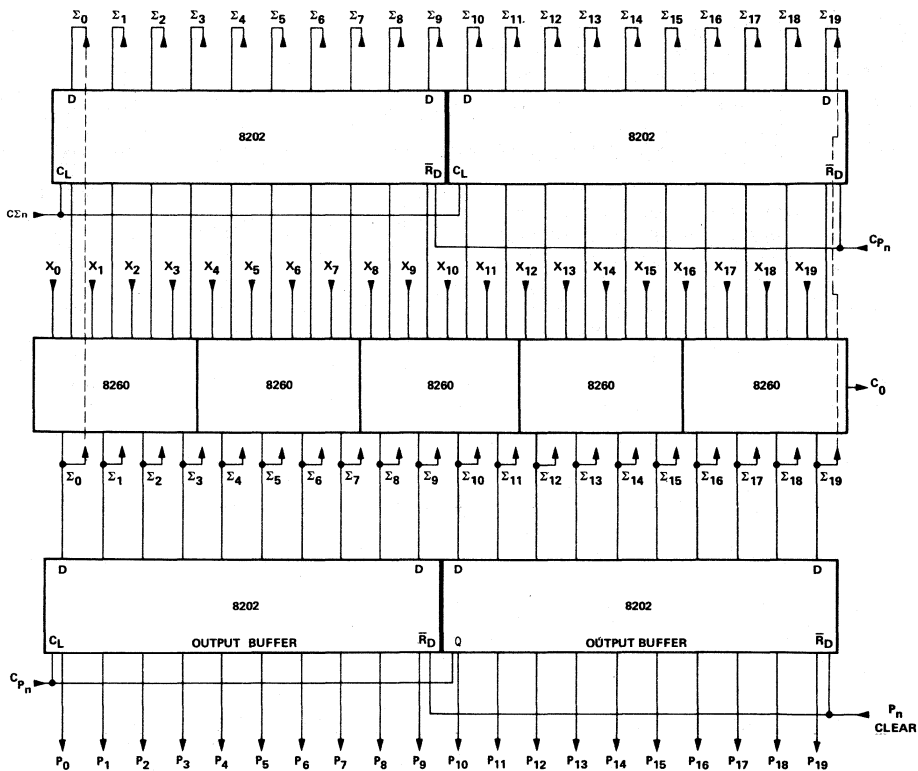


Total Package Count = 1-8202; 1-8880

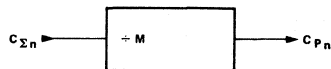


TYPICAL APPLICATIONS (Cont'd)

MULTIPLICATION AT 10MHz OF A 20-BIT BINARY WORD



$P_n = (X_n)M$  WHERE  $X_n \equiv$  MULTIPLICAND  
 $M \equiv$  MULTIPLIER  
 TOTAL PACKAGE COUNT = 9 PACKAGES (4-8202'S AND 5-8260'S)



#### DESCRIPTION

The 8-Input Digital Multiplexer is the logical equivalent of a single-pole, 8 position switch whose position is specified by a 3-bit input address.

The 8230 incorporates an INHIBIT input which, when low, allows the one-of-eight inputs selected by the address to appear on the  $f$  output and, in complement, on the  $\bar{f}$  output. With the INHIBIT input high, the  $f$  output is unconditionally low and the  $\bar{f}$  output is unconditionally high. The 8230 is a functional and pin-for-pin replacement for the 9312.

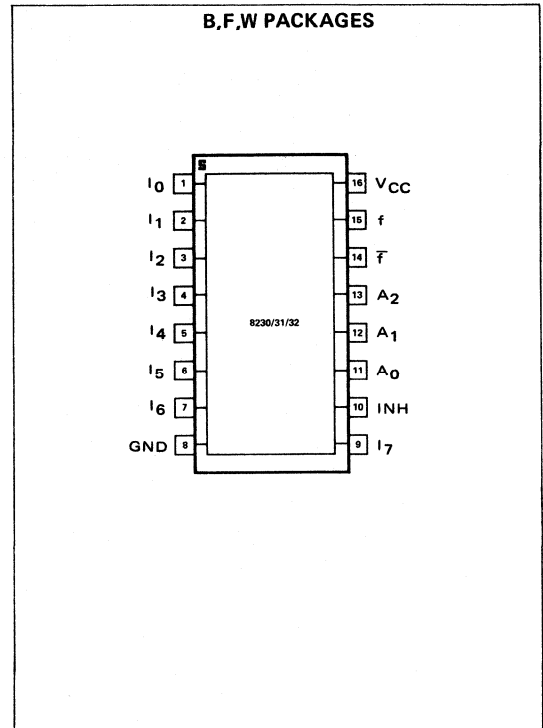
The 8231 is a variation of the 8230 that provides open collector output  $\bar{f}$  for expansion of input terms. The 8232 is similar to the 8230 except in the effect of the INHIBIT input on the  $\bar{f}$  output. With the INHIBIT low, the selected input appears at the  $f$  output and, in complement, on the  $\bar{f}$  output. With the INHIBIT input high, both the  $f$  and the  $\bar{f}$  output are unconditionally low.

#### TRUTH TABLE

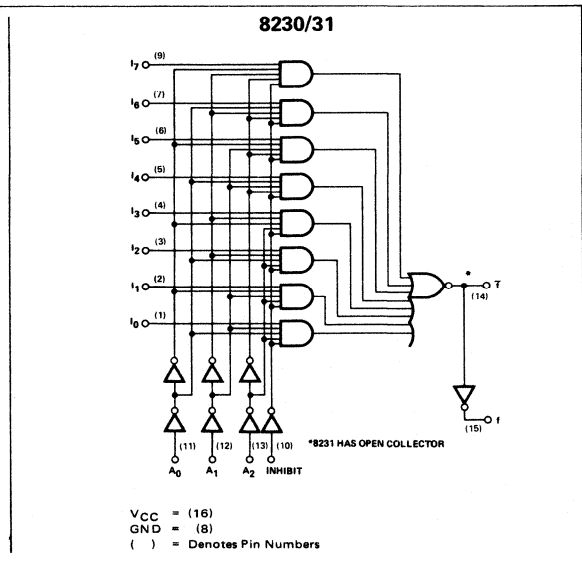
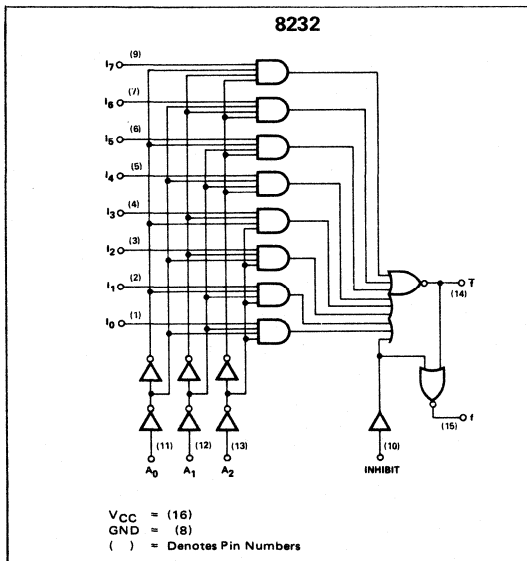
ADDRESS			DATA INPUTS								OUTPUT				
A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	I <sub>7</sub>	I <sub>6</sub>	I <sub>5</sub>	I <sub>4</sub>	I <sub>3</sub>	I <sub>2</sub>	I <sub>1</sub>	I <sub>0</sub>	INH	f	8230 8231 8232	8232 $\bar{f}$	
0	0	0	x	x	x	x	x	x	x	x	1	0	1	0	0
0	0	1	x	x	x	x	x	x	x	x	1	0	1	0	0
0	1	0	x	x	x	x	x	x	x	x	0	1	0	0	0
0	1	1	x	x	x	x	x	x	x	x	0	1	0	0	0
1	0	0	x	x	x	x	x	x	x	x	0	0	1	0	0
1	0	1	x	x	x	x	x	x	x	x	0	0	1	0	0
1	1	0	x	x	x	x	x	x	x	x	0	0	1	0	0
1	1	1	x	x	x	x	x	x	x	x	0	0	1	0	0
0	0	0	0	x	x	x	x	x	x	x	0	0	1	1	1
0	0	1	0	x	x	x	x	x	x	x	0	0	0	1	1
0	1	0	0	x	x	x	x	x	x	x	0	0	1	1	1
0	1	1	0	x	x	x	x	x	x	x	0	0	1	1	1
1	0	0	0	x	x	x	x	x	x	x	0	0	1	1	1
1	0	1	0	x	x	x	x	x	x	x	0	0	1	1	1
1	1	0	0	x	x	x	x	x	x	x	0	0	1	1	1
1	1	1	0	x	x	x	x	x	x	x	0	0	1	1	1
x	x	x	x	x	x	x	x	x	x	x	1	0	1	0	0

x = don't care

#### PIN CONFIGURATIONS (Top View)



#### LOGIC DIAGRAMS



**SIGNETICS 8-INPUT DIGITAL MULTIPLEXER ■ 8230/31/32**

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	INH	DATA INPUT In	OUTPUTS	
"1" Output Voltage, Output f	2.6	3.5		V	*	*	*	0.8V	2.0V	-800μA	6, 9
Output $\bar{f}$ (8230, 8232)	2.6	3.5		V	*	*	*	2.0V	*	-800μA	6, 9
"1" Output Leakage Current, Output $\bar{f}$ (8231)			150	μA	0.8V	2.0V	2.0V	2.0V	0.6V		11
"0" Output Voltage			0.4	V	0.8V	0.8V	0.8V	0.8V	0.8V	16mA	7, 9
"1" Input Current											
Inputs A <sub>n</sub> , I <sub>n</sub>			40	μA	4.5V	4.5V	4.5V		4.5V		
Input INH, 8230 & 8231			80	μA				4.5V			
Input INH, 8232			80	μA				4.5V			
"0" Input Current											
A <sub>n</sub> , I <sub>n</sub> , INH (8230 & 8231)	-0.1		-1.6	mA	0.4V	0.4V	0.4V		0.4V		
INH, (8232)	-0.1		-3.2	mA				0.4V			

T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	A	A	A	INH	DATA INPUT In	OUTPUTS f $\bar{f}$	
Propagation Delay											
A <sub>n</sub> to $\bar{f}$ (8230, 8232)		19	30	ns							8
A <sub>n</sub> to $\bar{f}$ (8231)		17	30	ns							8
I <sub>n</sub> to $\bar{f}$ (8230, 8232)		11	20	ns							8
$\bar{f}$ to f		10	15	ns							8
I <sub>n</sub> to $\bar{f}$ (8231)		13	24	ns							8
INH to $\bar{f}$ (8230, 8231)		18	30	ns							8
INH to f or $\bar{f}$ (8232)		11	20	ns							8
Power Consumption/Supply Current											
8230, 8231		184/35	250/47.7	mW/mA	4.5V	4.5V	4.5V	4.5V	0V		10
8232		173/33	262/50.0	mW/mA	4.5V	4.5V	4.5V	4.5V	0V		10
Output Short Circuit Current											
Output f	-20		-70	mA	0V	0V	0V	0V	4.5V	0V	10, 12
Output $\bar{f}$ (8230, 8232)	-20		-70	mA	0V	0V	0V	0V	0V	0V	10, 12
Input Voltage Rating	5.5			V	10mA	10mA	10mA	10mA	10mA		

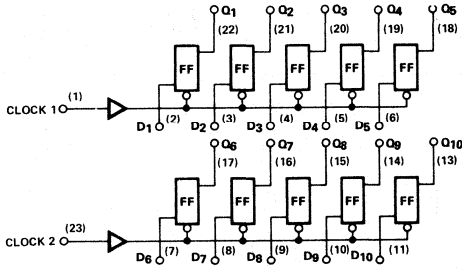
\*See Truth Table for Logical Conditions

**NOTES:**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>. Refer to AC Test Figures.
- By DC tests per the truth table, all inputs have guaranteed thresholds of 0.8V for logical "0" and 2.0V for logical "1".
- All I<sub>n</sub> data inputs are at 0V. V<sub>CC</sub> = 5.25V.
- Connect an external 1k resistor from V<sub>CC</sub> to the output terminal for this test.
- Not more than one output should be shorted at a time.

LOGIC DIAGRAMS AND TRUTH TABLES

DUAL 5-BIT BUFFER REGISTER

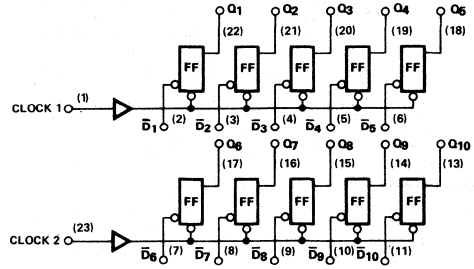


D <sub>n</sub>	Q <sub>n+1</sub>
1	1
0	0

V<sub>CC</sub> = (24)  
 GND = (12)  
 ( ) = Denotes Pin Numbers

8200

DUAL 5-BIT BUFFER REGISTER—INVERTED INPUTS

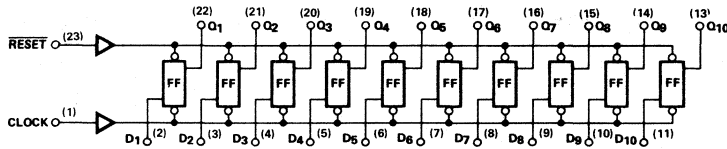


D̄ <sub>n</sub>	Q <sub>n+1</sub>
1	0
0	1

V<sub>CC</sub> = (24)  
 GND = (12)  
 ( ) = Denotes Pin Numbers

8201

10-BIT BUFFER REGISTER

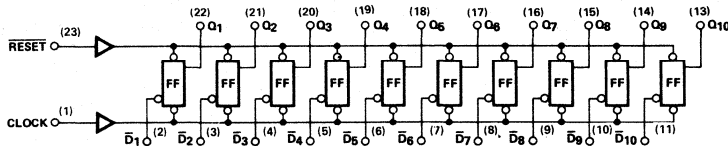


D <sub>n</sub>	RESET	Q <sub>n+1</sub>
1	1	1
0	1	0

V<sub>CC</sub> = (24)  
 GND = (12)  
 ( ) = Denotes Pin Numbers

RESET = 0 ⇒ Q = 0  
 (OVERRIDES CLOCK)  
 n IS TIME PRIOR TO CLOCK  
 n+1 IS TIME FOLLOWING CLOCK

10-BIT BUFFER REGISTER—INVERTED INPUTS



D <sub>n</sub>	RESET	Q <sub>n+1</sub>
0	1	1
1	1	0

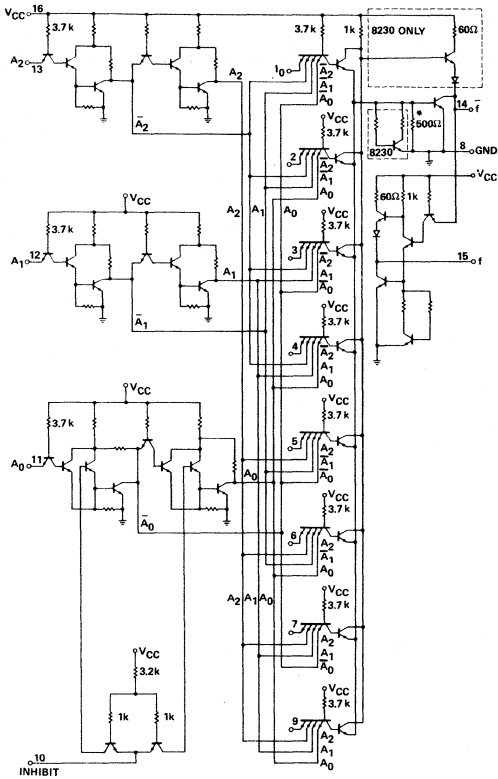
V<sub>CC</sub> = (24)  
 GND = (12)  
 ( ) = Denotes Pin Numbers

RESET = 0 ⇒ Q = 0  
 (OVERRIDES CLOCK)  
 n IS TIME PRIOR TO CLOCK  
 n+1 IS TIME FOLLOWING CLOCK

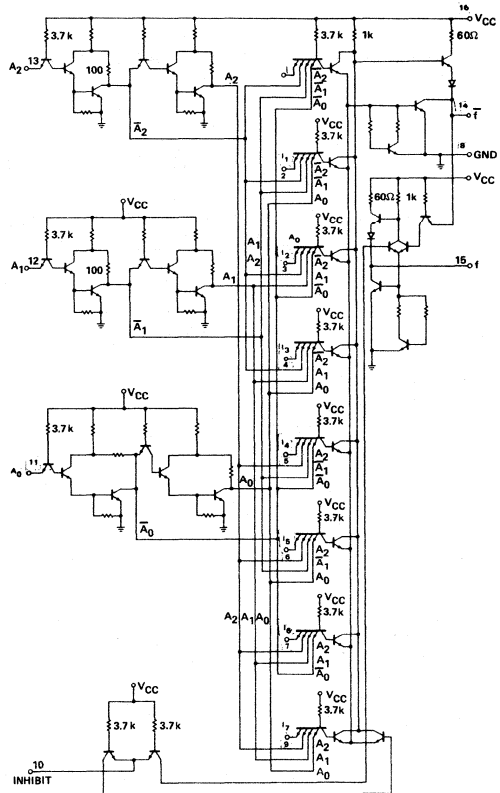
8203

**SCHEMATIC DIAGRAMS:**

**8230 AND 8231**



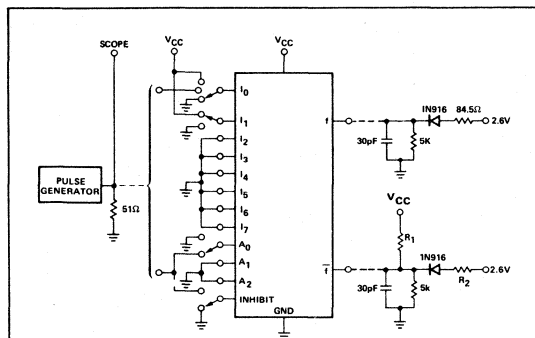
**8232**



\*500 Resistor on 8231 only.  
 Note: All inputs have diode clamping. All outputs have isolation diodes.

Note: All inputs have diode clamping. All outputs have isolation diodes.

AC TEST FIGURE AND WAVEFORMS

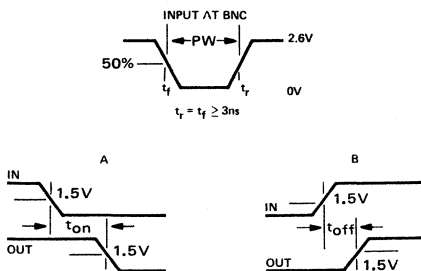


	8230/32	8231
R <sub>1</sub>	∞	360Ω
R <sub>2</sub>	84.5Ω	440Ω

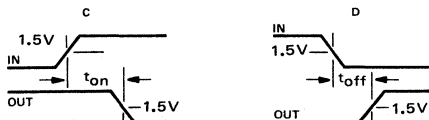
NOTES:

- 5K, 30pF load includes test jigs and scope impedance.
- Scope terminals to be ≤ 1½" from package pins.
- See truth table for logical conditions.

NON-INVERTING PATHS



INVERTING PATHS



AC TEST CONDITIONS

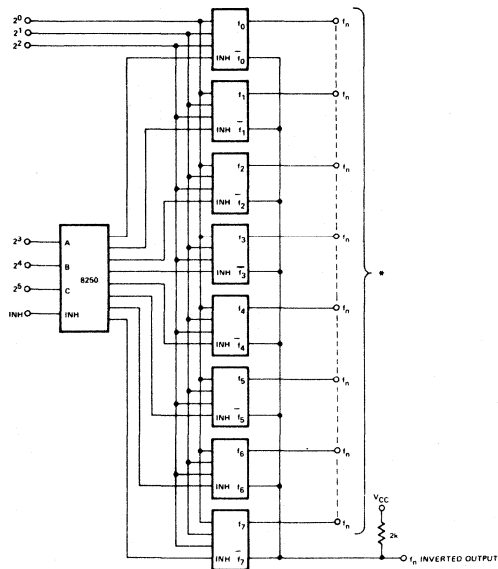
STEP NO.	TYPE/S	DELAY FROM-TO	INPUTS				WAVE-FORM TYPE
			I <sub>0</sub>	I <sub>1</sub>	A <sub>0</sub>	INH	
1	ALL	A <sub>0</sub> to $\bar{f}$	0 V	V <sub>CC</sub>	P.G.	0 V	C, D
2	ALL	I <sub>0</sub> to $\bar{f}$	P. G.	0 V	0 V	0 V	C, D
3	ALL	f to f*	P. G.	0 V	0 V	0 V	C, D
4	8230	INH to $\bar{f}$	V <sub>CC</sub>	0 V	0 V	P. G.	A, B
5	8231	INH to $\bar{f}$	0 V	0 V	0 V	P. G.	C, D
6	8232	INH to f	V <sub>CC</sub>	0 V	0 V	P. G.	C, D

NOTE: 1. P. G. = Pulse Generator

\*Both f and  $\bar{f}$  are simultaneously loaded.

TYPICAL APPLICATIONS

EXPANSION OF 8231 TO MULTIPLEXER 64 LINES



\*f<sub>n</sub> = f<sub>0</sub> + f<sub>1</sub> + f<sub>2</sub> ..... f<sub>7</sub>

True Output

All Outputs may be tied together to drive 8x16mA (eight 1.6mA F.O.) or each Output may drive separately ten 1.6mA F.O.

Note:

Each 8231 has 8 data inputs which are not shown.

#### DESCRIPTION

These devices are 2-input, 4-Bit Digital Multiplexers designed for general purpose data-selection applications.

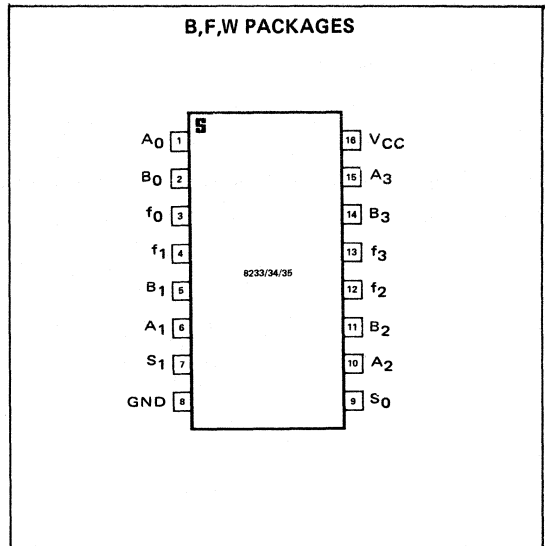
The 8233 features *non-inverting* data paths; and, the 8234 features *inverting* data paths.

The 8235 is designed for input to adders, registers and general paralleled data handling due to its capability to perform **CONDITIONAL COMPLEMENTING (TRUE/COMPLEMENT)**. When the two inputs for each bit position ( $A_i, B_i$ ) are connected together, the  $f$  output will provide either the *True* or *Complement* of the input data. This capability is especially useful for transferring data into parallel adders where both true data for adding or multiplying and also complemented data for subtracting or dividing are needed.

The 8234 and 8235 designs have open collector outputs which permit direct wiring to other open collector outputs (collector logic) to yield "free" four-bit words. As many as one hundred four-bit words can be multiplexed by using fifty 8234/8235s in the WIRED-AND mode.

The inhibit state  $S_0 = S_1 = 1$  can be used to facilitate transfer operations in an arithmetic section.

#### PIN CONFIGURATIONS (Top View)

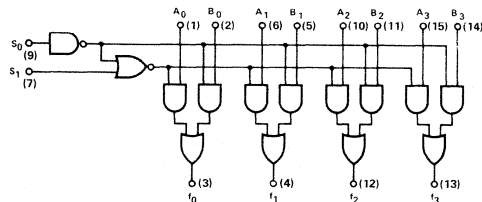


#### LOGIC DIAGRAM AND TRUTH TABLES

**8233 (ACTIVE PULL-UP)**

$S_0$	$S_1$	$f_n$
0	0	B
1	0	A
0	1	B
1	1	0

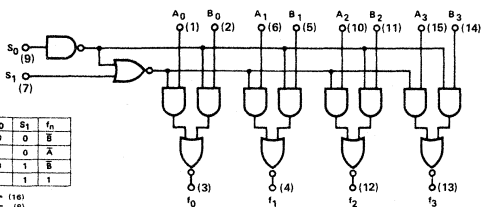
$V_{CC}$  = (16)  
 $GND$  = (8)  
 ( ) = Denotes Pin Numbers



**8234 (OPEN COLLECTOR)**

$S_0$	$S_1$	$f_n$
0	0	B
1	0	A
0	1	B
1	1	1

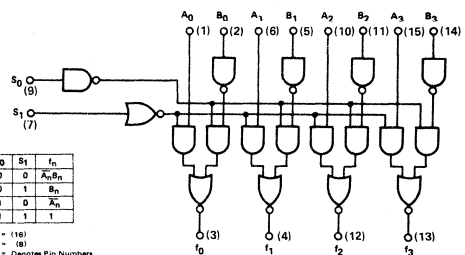
$V_{CC}$  = (16)  
 $GND$  = (8)  
 ( ) = Denotes Pin Numbers



**8235 (OPEN COLLECTOR)**

$S_0$	$S_1$	$f_n$
0	0	$A_n B_n$
0	1	$\bar{B}_n$
1	0	$\bar{A}_n$
1	1	1

$V_{CC}$  = (16)  
 $GND$  = (8)  
 ( ) = Denotes Pin Numbers



**SIGNETICS 2-INPUT 4-BIT DIGITAL MULTIPLEXER ■ 8233/34/35**

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
					INPUTS					
	MIN.	TYP.	MAX.	UNITS	A <sub>n</sub>	B <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>		
"1" Output Voltage (8233)	2.6	3.5		V	2.0V	2.0V	0.8V	0.8V	-800μA	6
"0" Output Voltage (8233)			0.4	V	0.8V	2.0V	2.0V	0.8V	16mA	7
"0" Output Voltage (8234)			0.4	V	0V	2.0V	0.8V	0.8V	16mA	7
"0" Output Voltage (8235)			0.4	V	2.0V	2.0V	2.0V	0.8V	16mA	7
"1" Output Leakage Current (8234)			100	μA	2.0V	2.0V	2.0V	2.0V	5.0V	8
"1" Output Leakage Current (8235)			100	μA	2.0V	2.0V	2.0V	2.0V	5.0V	8
"0" Input Current										
A <sub>n</sub>	-0.1		-1.6	mA	0.4V	4.5V		0V		
B <sub>n</sub>	-0.1		-1.6	mA	4.5V	0.4V	0V	0V		
S <sub>0</sub>	-0.1		-1.6	mA			0.4V			
S <sub>1</sub>	-0.1		-1.6	mA				0.4V		
"1" Input Current										
A <sub>n</sub>			40	μA	4.5V	0V				
B <sub>n</sub>			40	μA	0V	4.5V				
S <sub>0</sub>			40	μA			4.5V			
S <sub>1</sub>			40	μA				4.5V		
Input Voltage Rating										
A <sub>n</sub>	5.5			V	10mA	0V				
B <sub>n</sub>	5.5			V	0V	10mA				
S <sub>0</sub>	5.5			V			10mA			
S <sub>1</sub>	5.5			V				10mA		
Output Short Circuit Current (8233)	-20		-70	mA	5V	5V	0V	0V	0V	10, 11
Input Clamp Voltage										
A <sub>n</sub>			-1.5	V	-12mA					
B <sub>n</sub>			-1.5	V		-12mA				
S <sub>0</sub>			-1.5	V			-12mA			
S <sub>1</sub>			-1.5	V				-12mA		



**SIGNETICS 2-INPUT 4-BIT DIGITAL MULTIPLEXER ■ 8233/34/35**

$T_A = 25^\circ \text{C}$  and  $V_{CC} = 5.0\text{V}$

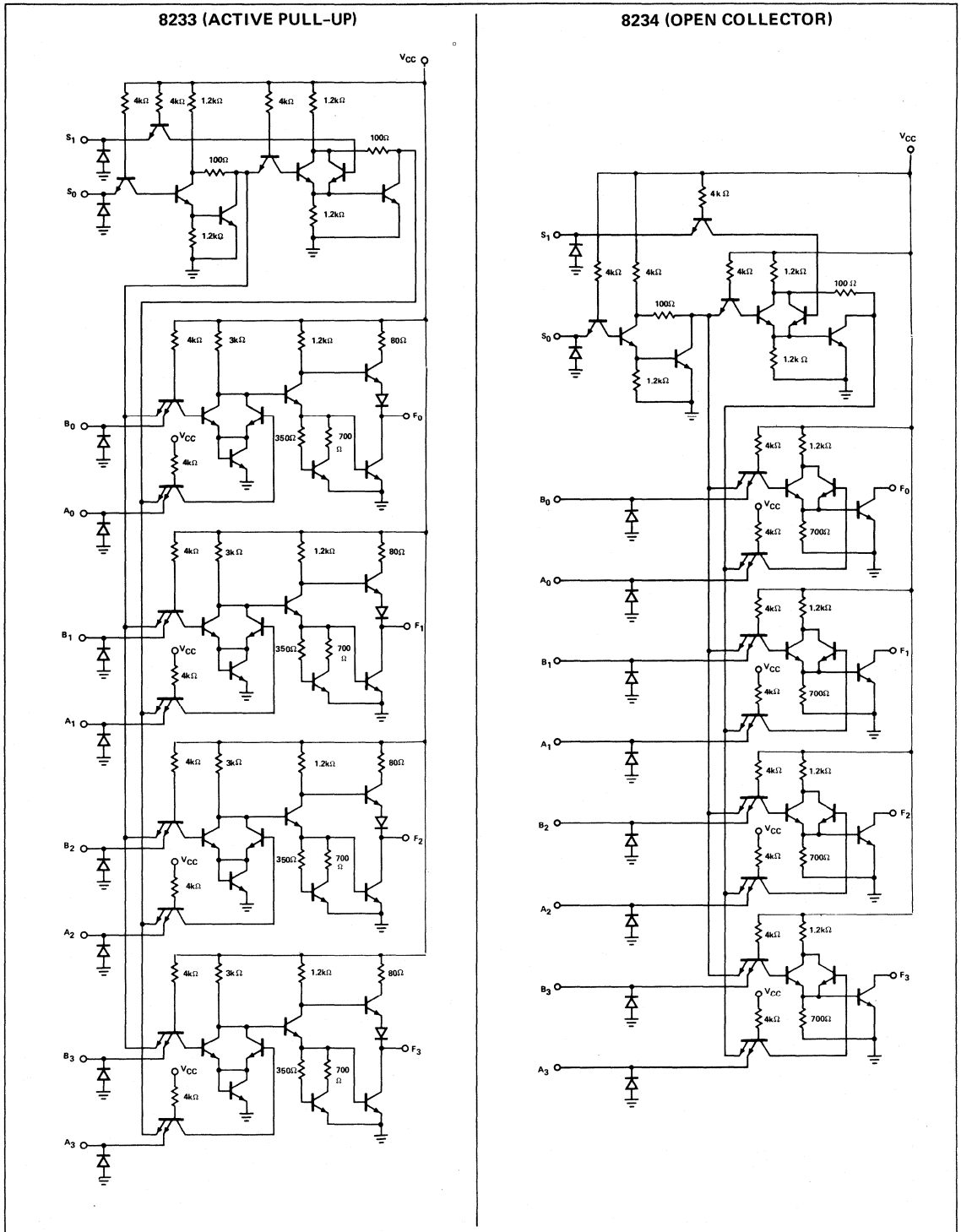
CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
					INPUTS					
	MIN.	TYP.	MAX.	UNITS	A <sub>n</sub>	B <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>		
Power/Current										
Consumption:										
8233		200/38	252/48	mW/mA		0V		0V		10
8234		160/31	210/40	mW/mA		0V		0V		10
8235		230/44	310/59	mW/mA		4.5V		4.5V		10
8233 Turn-On Times, t <sub>ON</sub>										
A <sub>n</sub> , B <sub>n</sub> to f <sub>n</sub>		16	25	ns						9
S <sub>0</sub> to f <sub>n</sub>		27	38	ns						9
S <sub>1</sub> to f <sub>n</sub>		27	38	ns						9
8233 Turn-Off Times, t <sub>OFF</sub>										
A <sub>n</sub> , B <sub>n</sub> to f <sub>n</sub>		16	25	ns						9
S <sub>0</sub> to f <sub>n</sub>		27	38	ns						9
S <sub>1</sub> to f <sub>n</sub>		27	38	ns						9
8234 Turn-On Times, t <sub>ON</sub>										
A <sub>n</sub> , B <sub>n</sub> to f <sub>n</sub>		16	25	ns						9
S <sub>0</sub> to f <sub>n</sub>		27	38	ns						9
S <sub>1</sub> to f <sub>n</sub>		27	38	ns						9
8234 Turn-Off Times, t <sub>OFF</sub>										
A <sub>n</sub> , B <sub>n</sub> to f <sub>n</sub>		16	25	ns						9
S <sub>0</sub> to f <sub>n</sub>		27	38	ns						9
S <sub>1</sub> to f <sub>n</sub>		27	38	ns						9
8235 Turn-On Times, t <sub>ON</sub>										
A <sub>n</sub> to f <sub>n</sub>		16	25	ns						9
B <sub>n</sub> to f <sub>n</sub>		24	35	ns						9
S <sub>0</sub> to f <sub>n</sub>		27	38	ns						9
S <sub>1</sub> to f <sub>n</sub>		27	38	ns						9
8235 Turn-Off Times, t <sub>OFF</sub>										
A <sub>n</sub> to f <sub>n</sub>		16	25	ns						9
B <sub>n</sub> to f <sub>n</sub>		24	35	ns						9
S <sub>0</sub> to f <sub>n</sub>		27	38	ns						9
S <sub>1</sub> to f <sub>n</sub>		27	38	ns						9

**NOTES:**

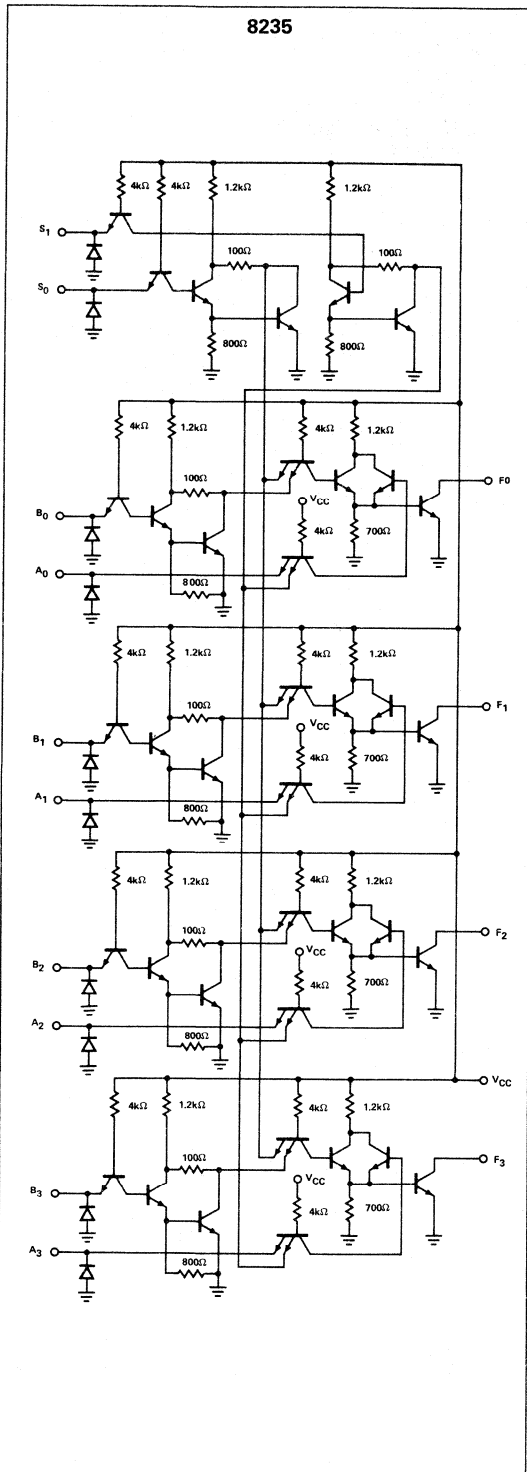
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Connect an external 1k ±1% resistor from V<sub>CC</sub> to the output for this test.
- Reference AC Test Circuit, Waveforms and Test Tables.
- V<sub>CC</sub> = 5.25V.
- Not more than one output should be shorted at a time.

SIGNETICS 2-INPUT 4-BIT DIGITAL MULTIPLEXER ■ 8233/34/35

SCHEMATIC DIAGRAMS



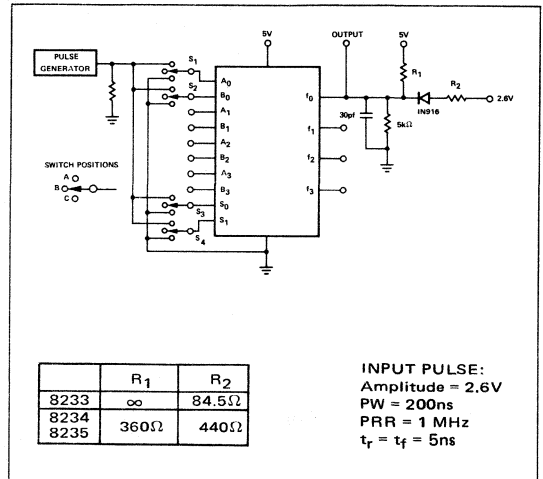
**SCHEMATIC DIAGRAMS (Cont'd)**



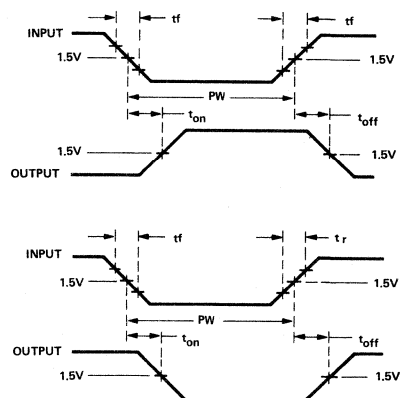
**PROPAGATION DELAY TEST TABLE**

PRODUCT	PATH	PARAMETER	S <sub>1</sub>	S <sub>2</sub>	S <sub>3</sub>	S <sub>4</sub>
ALL	A <sub>0</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	a	b	b	c
8233 8234	B <sub>0</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	c	a	c	b
8233 8234	S <sub>0</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	b	b	a	b
8233 8234	S <sub>0</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	b	c	a	c
8235	B <sub>0</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	c	a	c	b
8235	B <sub>0</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	b	c	a	b
8235	S <sub>1</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	b	b	c	a
8233 8234	S <sub>1</sub> to f <sub>0</sub>	$t_{on}$ $t_{off}$	b	c	b	a

**AC TEST FIGURE AND WAVEFORMS**



**PULSE REQUIREMENTS**



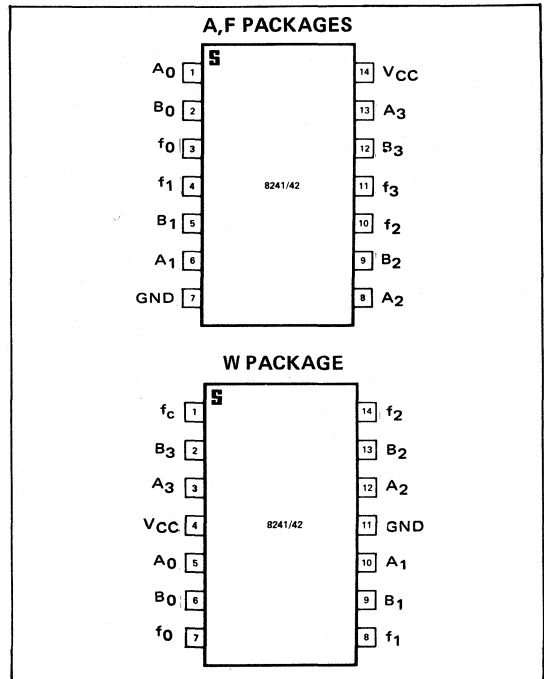
#### DESCRIPTION

The 8241 contains four independent gating structures to perform the Exclusive-OR function on two input variables.

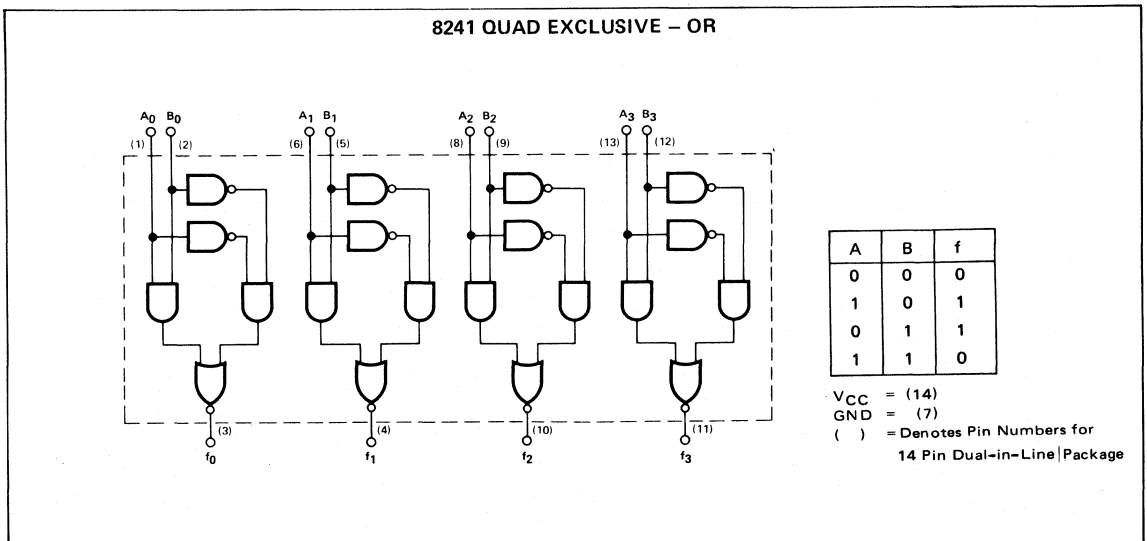
The output of the 8241 employs the totem-pole structure characteristic of TTL devices.

The 8242 contains four independent Exclusive-NOR gates which may be used to implement digital comparison functions. The 8242 outputs are bare collector to facilitate implementation of multiple-bit comparisons; a 4-bit comparison is made by connecting the outputs of the four independent gates together.

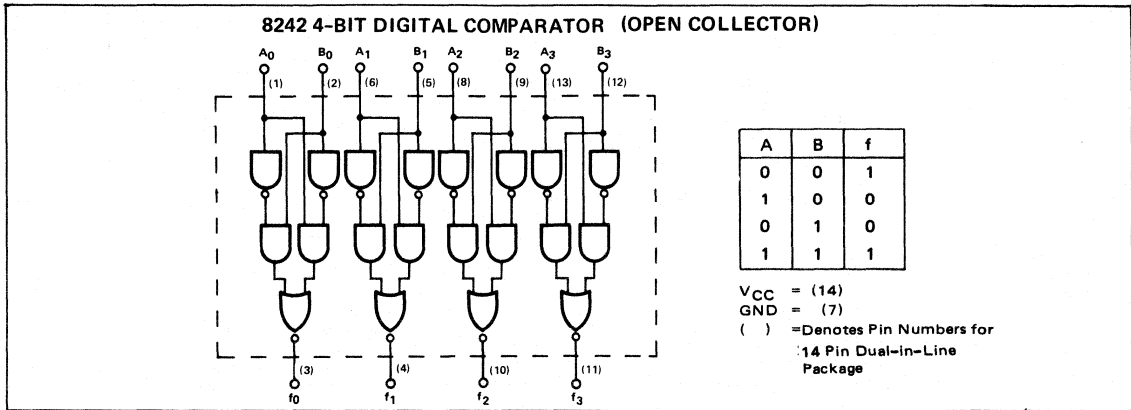
#### PIN CONFIGURATIONS (Top View)



#### LOGIC DIAGRAMS AND TRUTH TABLES



LOGIC DIAGRAMS AND TRUTH TABLES (Cont'd)



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage (8241)

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUTS	
					A	B		
Output "1" Voltage	2.6	3.5		V	2.0	0.8	-800 $\mu$ A	7
Output "0" Voltage			0.4	V	2.0	2.0	16mA	8
Input "1" Current			80	$\mu$ A	4.5	4.5V		11
Input "0" Current	-0.1		-3.2	mA	0.4	0.4		12
Power/Current Consumption		225/42.4	300/57.1	mW/mA				13
Output Short Circuit Current	-20		-70	mA			0V	6, 13
Input Voltage Rating								
A Input	5.5			V	10mA	0V		
B Input	5.5			V	0V	10mA		

$T_A = 25^\circ C$  and  $V_{CC} = 5.0V$  (8241)

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUTS	
					A	B		
Propagation Delay		17	23	ns				9
		11	17	ns				

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage (8242)

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUT	
					A	B		
Output "1" Leakage Current			25	$\mu$ A	2.0	2.0	25mA	10
Output "0" Voltage			0.4	V	2.0	0.8		8
Input "1" Current			80	$\mu$ A	4.5	4.5V		11
Input "0" Current	-0.1		-3.2	mA	0.4	0.4		12
Power/Current Consumption		170/32	250/47.5	mW/mA	0.4	0.4		13
Input Voltage Rating								
A Input	5.5			V	10mA	0V		
B Input	5.5			V	0V	10mA		10

T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

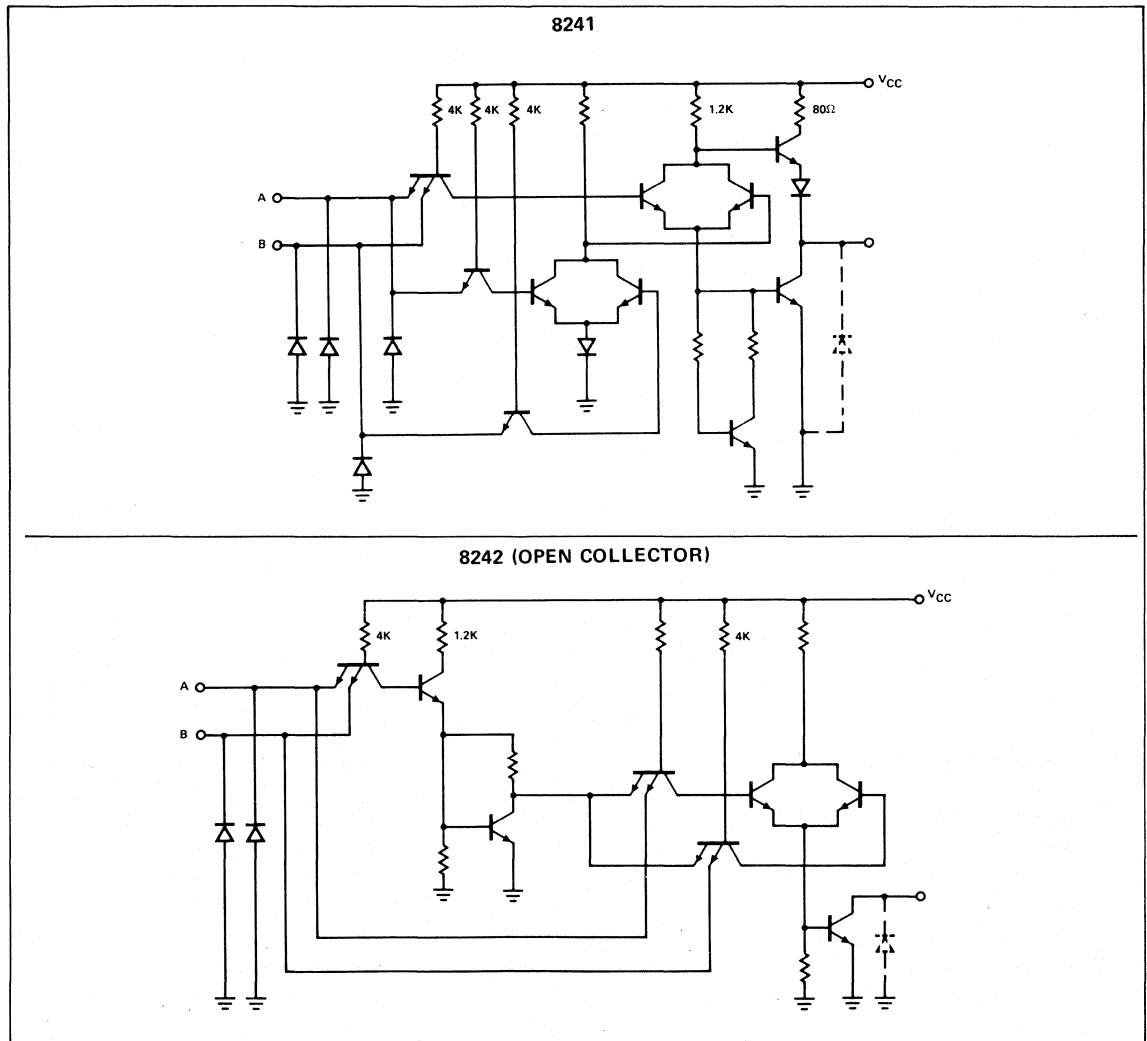
(8242)

CHARACTERISTICS	LIMITS				TEST CONDITIONS			INPUTS
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUTS	
					A	B		
Inverting Path t <sub>on</sub>		12	20	ns				9
Propagation Delay Non-Inverting Path t <sub>off</sub>		14	23	ns				
t <sub>on</sub>		14	21	ns				
t <sub>off</sub>		20	28	ns				

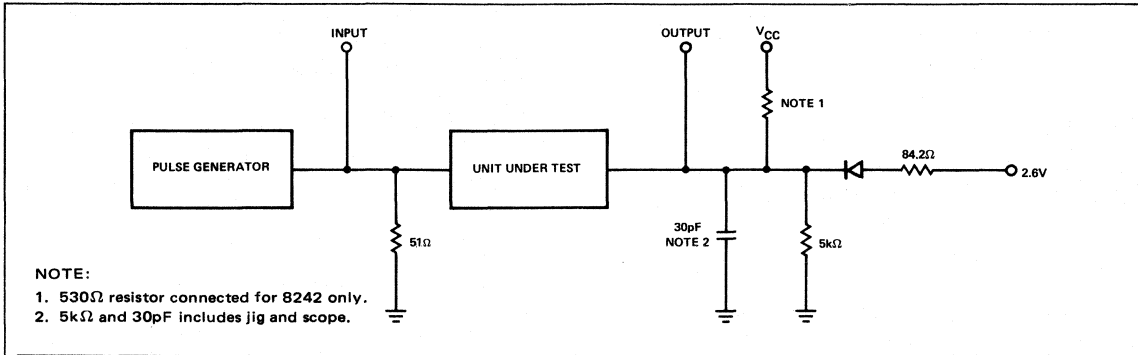
NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Not more than one output should be shorted at a time.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figure and waveforms.
- Connect an external 1K ±1% resistor from V<sub>CC</sub> to the output terminal for this test.
- A and B are tested separately. When A is 4.5V, B is 0V, and vice versa.
- A and B are tested separately. When A is 0.4V, B is 5.25V, and vice versa.
- V<sub>CC</sub> = 5.25V.

SCHEMATIC DIAGRAMS

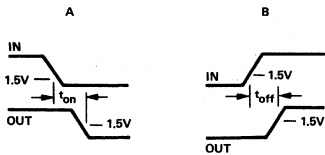


AC TEST FIGURE AND WAVEFORMS

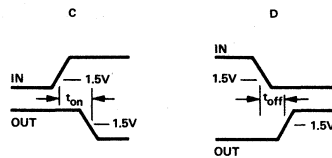


PROPAGATION DELAY WAVEFORMS

NON-INVERTING PATHS

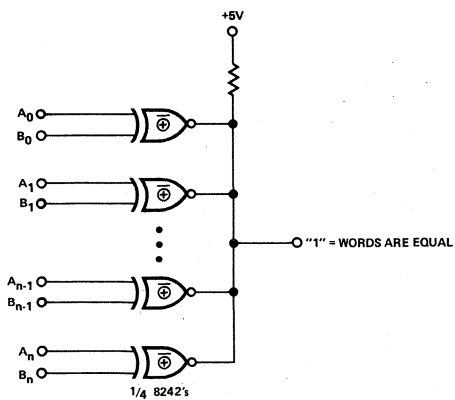


INVERTING PATHS

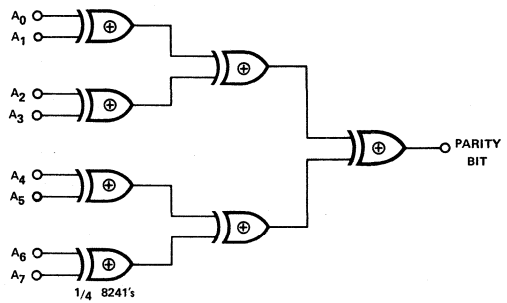


TYPICAL APPLICATIONS

EQUALITY GATE USED FOR COMPARISON



PARITY GENERATOR/TESTER



### DIGITAL 8000 SERIES TTL/MSI

#### DESCRIPTION

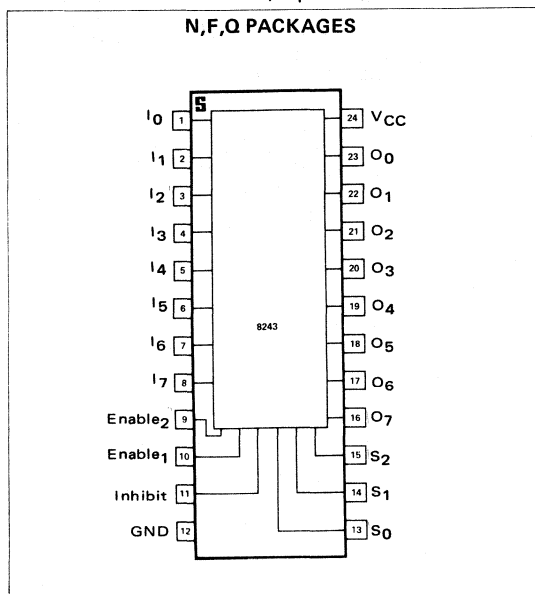
The 8243 8-Bit Position Scaler is an MSI array of approximately 70 gate complexity. The primary function of the 8243 is to scale (or shift) data bit positions by a selection of a 3-bit binary selector code.

The most significant bit input ( $I_7$ ) may be shifted 8 positions to the least significant bit output ( $O_0$ ). At zero shift, or scale select, all eight input data bits are transferred and inverted to their respective outputs, ( $I_0$  to  $O_0$ ,  $I_1$  to  $O_1$ ,  $I_2$  to  $O_2$ , etc.) At a shift, or scale select, of one, each input bit ( $I_n$ ) will shift to the next lower output bit ( $O_{n-1}$ ). See truth table for other shift codes.

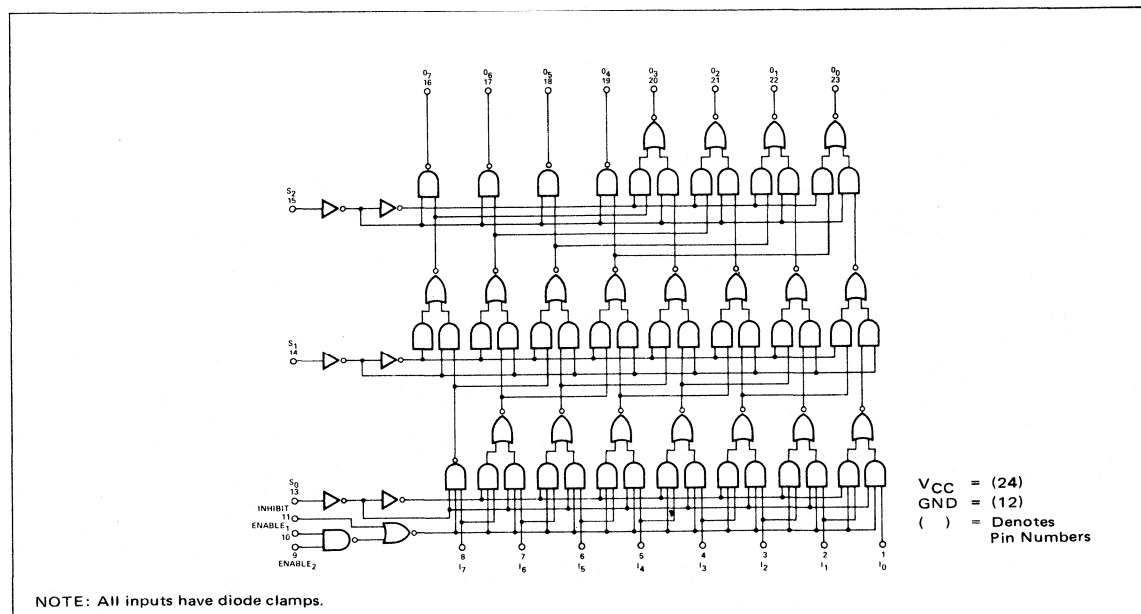
The 8243's advantages over shift registers are the speed of operation and lower complexity of external logic required to effect a scale function. The speed of the 8243 Scaler is a function of gate propagation delays—the speed of equivalent shift registers is the time for clock periods plus the propagation delay to effect a scale function.

The 8243 is provided with open collector outputs to provide expansion to larger scaling functions. Data input logic zero loading is reduced to less than  $-100\mu\text{A}$  when the unit is disabled.

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM AND TRUTH TABLE





## TRUTH TABLE

INHIBIT	ENABLE 1 & 2	S <sub>0</sub>	S <sub>1</sub>	S <sub>2</sub>	O <sub>0</sub>	O <sub>1</sub>	O <sub>2</sub>	O <sub>3</sub>	O <sub>4</sub>	O <sub>5</sub>	O <sub>6</sub>	O <sub>7</sub>
0	1	0	0	0	$\bar{O}_0$	$\bar{O}_1$	$\bar{O}_2$	$\bar{O}_3$	$\bar{O}_4$	$\bar{O}_5$	$\bar{O}_6$	$\bar{O}_7$
0	1	1	0	0	$\bar{O}_1$	$\bar{O}_2$	$\bar{O}_3$	$\bar{O}_4$	$\bar{O}_5$	$\bar{O}_6$	$\bar{O}_7$	1
0	1	0	1	0	$\bar{O}_2$	$\bar{O}_3$	$\bar{O}_4$	$\bar{O}_5$	$\bar{O}_6$	$\bar{O}_7$	1	1
0	1	1	1	0	$\bar{O}_3$	$\bar{O}_4$	$\bar{O}_5$	$\bar{O}_6$	$\bar{O}_7$	1	1	1
0	1	0	0	1	$\bar{O}_4$	$\bar{O}_5$	$\bar{O}_6$	$\bar{O}_7$	1	1	1	1
0	1	1	0	1	$\bar{O}_5$	$\bar{O}_6$	$\bar{O}_7$	1	1	1	1	1
0	1	0	1	1	$\bar{O}_6$	$\bar{O}_7$	1	1	1	1	1	1
0	1	1	1	1	$\bar{O}_7$	1	1	1	1	1	1	1
1	X	X	X	X	1	1	1	1	1	1	1	1
X	0	X	X	X	1	1	1	1	1	1	1	1

X Indicates either logic "1" or logic "0" may be present.

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS							NOTES
	MIN.	TYP.	MAX.	UNITS	I <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	S <sub>2</sub>	ENABLE 1&2	INHIBIT	OUTPUTS	
"1" Output Leakage Current			150	μA	0.8V	*	*	*	2.0V	0.8V		7
"0" Output Voltage			0.4	V	2.0V	*	*	*	2.0V	0.8V	12.8mA	7
"0" Input Current												
Data In (Disabled)			-100	μA	0.4V				0.8V	2.0V		
Data In (Enabled)	-0.1		-1.6	mA	0.4V	0.8V			2.0V	0.8V		
Select S <sub>n</sub>	-0.1		-1.6	mA		0.4V	0.4V	0.4V				
Inhibit	-0.1		-1.6	mA					0.4V	0.4V		
Enable 1 & 2	-0.1		-1.6	mA					0.4V	4.5V		11
"1" Input Current												
Data In			80	μA	4.5V	2.0V				2.0V		
Select S <sub>n</sub>			40	μA		4.5V	4.5V	4.5V				
Inhibit			40	μA					2.0V	4.5V		
Enable 1 & 2			40	μA					4.5V			12

T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS							NOTES
	MIN.	TYP.	MAX.	UNITS	I <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	S <sub>2</sub>	ENABLE 1&2	INHIBIT	OUTPUTS	
Propagation Delay												
Data In		20	32	ns								9, 10
Select S <sub>n</sub>		30	40	ns								
Inhibit		25	35	ns								
Enable 1 & 2		30	45	ns								
Power/Current		315/	500/	mW/								13
Consumption		60	75.2	mA								
Input Voltage Rating	5.5				10mA	10mA	10mA	10mA	10mA	10mA		

## NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive NAND logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Connect an external 1k resistor from V<sub>CC</sub> to the output terminal for this test.
- Manufacturer reserves the right to make design and process changes and improvements.
- Refer to AC Test figures.
- I<sub>n</sub> "0" threshold 0.7 volts for S8243.
- Input under test at 0.4V, other Enable Input tied to V<sub>CC</sub>.
- Input under test at 4.5V, other Enable Input, 0 volts.
- V<sub>CC</sub> = 5.25V.

AC TEST FIGURES AND WAVEFORMS

PROPAGATION DELAY, ENABLE TO OUTPUT

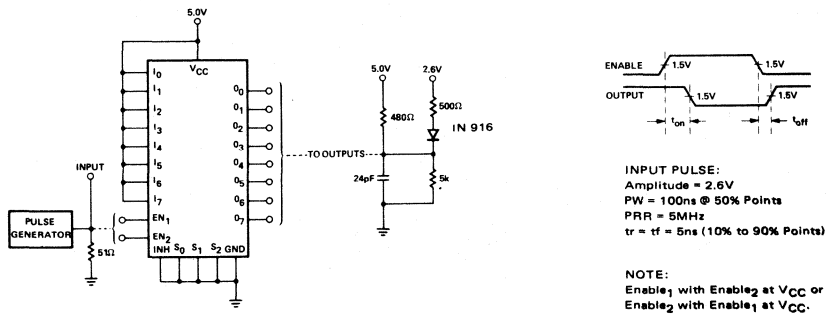


FIGURE 1

PROPAGATION DELAY, DATA INPUT TO DATA OUTPUT

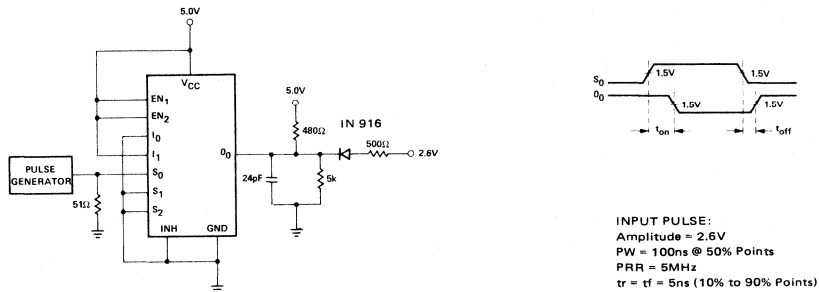


FIGURE 2

PROPAGATION DELAY, DATA SELECT TO OUTPUT

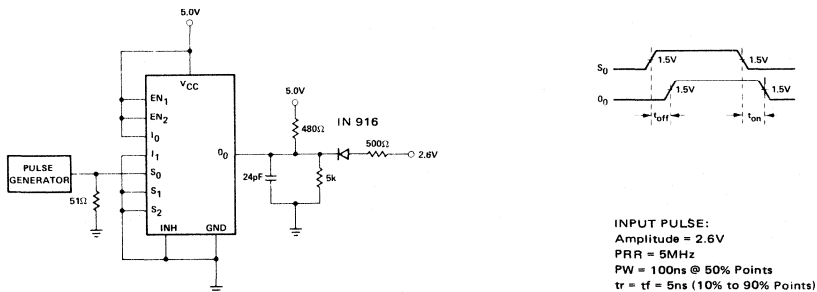


FIGURE 3

PROPAGATION DELAY, DATA SELECT TO OUTPUT

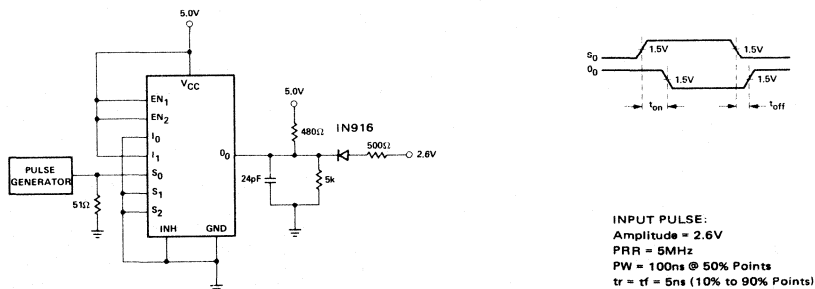
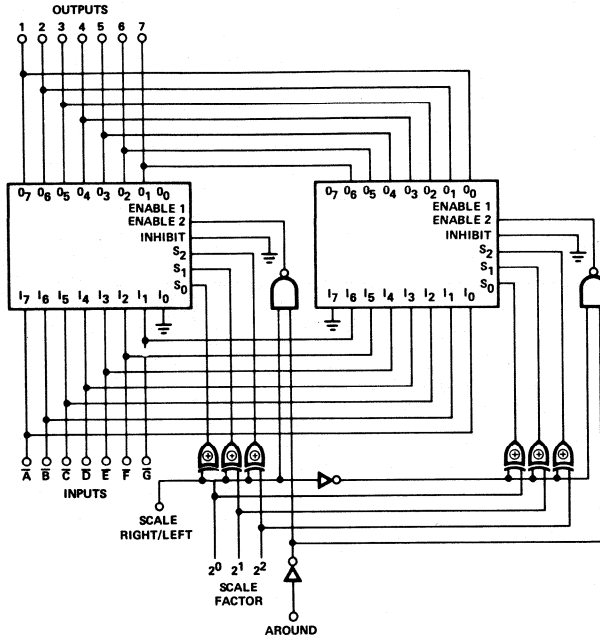


FIGURE 4

TYPICAL APPLICATIONS

BI-DIRECTIONAL 8-POSITION SHIFTER



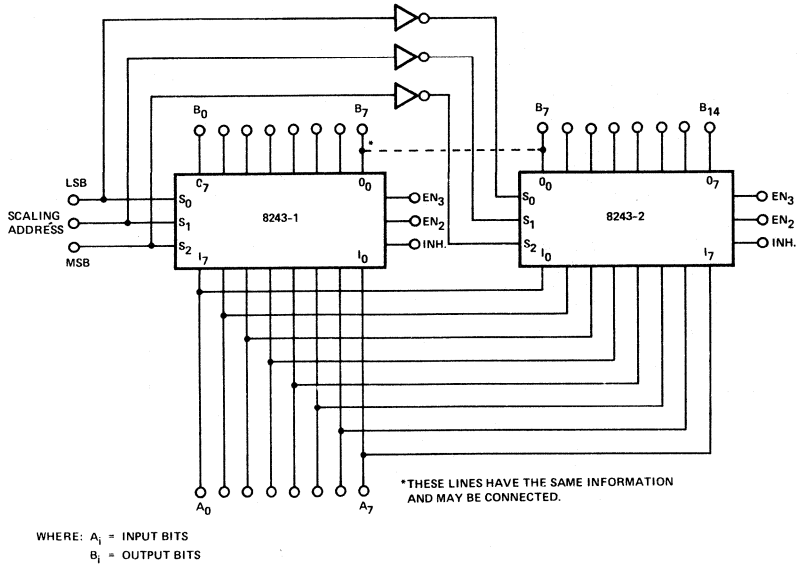
SCALE FACTOR	OUTPUTS								
	1	2	3	4	5	6	7		
0	A	B	C	D	E	F	G		SCALE RIGHT.
1	1	A	B	C	D	E	F		
2	1	1	A	B	C	D	E		
3	1	1	1	A	B	C	D		
4	1	1	1	1	A	B	C		
5	1	1	1	1	1	A	B		SCALE = 0
6	1	1	1	1	1	1	A		AROUND = 0
7	1	1	1	1	1	1	1		

SCALE FACTOR	OUTPUTS								
	1	2	3	4	5	6	7		
0	A	B	C	D	E	F	G		SCALE RIGHT
1	G	A	B	C	D	E	F		& AROUND
2	F	G	A	B	C	D	E		
3	E	F	G	A	B	C	D		
4	D	E	F	G	A	B	C		
5	C	D	E	F	G	A	B		SCALE = 0
6	B	C	D	E	F	G	A		AROUND = 1
7	A	B	C	D	E	F	G		

SCALE FACTOR	OUTPUTS								
	1	2	3	4	5	6	7		
0	A	B	C	D	E	F	G		SCALE LEFT
1	B	C	D	E	F	G	1		
2	C	D	E	F	G	1	1		
3	D	E	F	G	1	1	1		
4	E	F	G	1	1	1	1		
5	F	G	1	1	1	1	1		SCALE = 1
6	G	1	1	1	1	1	1		AROUND = 0
7	1	1	1	1	1	1	1		

SCALE FACTOR	OUTPUTS								
	1	2	3	4	5	6	7		
0	A	B	C	D	E	F	G		SCALE LEFT
1	B	C	D	E	F	G	A		& AROUND
2	C	D	E	F	G	A	B		
3	D	E	F	G	A	B	C		
4	E	F	G	A	B	C	D		
5	F	G	A	B	C	D	E		SCALE = 1
6	G	A	B	C	D	E	F		AROUND = 1
7	A	B	C	D	E	F	G		

ARRAY EXPANSION



TRUTH TABLE FOR ARRAY EXPANSION

SCALE ADDRESS		8243-1								8243-2							
MSB	LSB	$B_0$	$B_1$	$B_2$	$B_3$	$B_4$	$B_5$	$B_6$	$B_7$	$B_7$	$B_8$	$B_9$	$B_{10}$	$B_{11}$	$B_{12}$	$B_{13}$	$B_{14}$
0	0	0	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$	$\bar{A}_7$	1	1	1	1	1	1
0	0	1	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_6$	$\bar{A}_7$	1	1	1	1	1	1
0	1	0	1	1	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$	1	1	1	1
0	1	1	1	1	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$	1	1	1	1
1	0	0	1	1	1	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$	1	1	1
1	0	1	1	1	1	1	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$	1	1
1	1	0	1	1	1	1	1	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$	1
1	1	1	1	1	1	1	1	1	$\bar{A}_0$	$\bar{A}_0$	$\bar{A}_1$	$\bar{A}_2$	$\bar{A}_3$	$\bar{A}_4$	$\bar{A}_5$	$\bar{A}_6$	$\bar{A}_7$

#### PIN CONFIGURATIONS (Top View)

#### DESCRIPTION

The 8250, 8251 and 8252 are gate arrays for decoding and logic conversion applications.

The 8250 converts 3 lines of input to a one-of-eight output. The fourth input line (D) is utilized as an inhibit to allow use in larger decoding networks.

The 8251 and 8252 convert a 4 line input code (with 1-2-4-8 weighting) to a one-of-ten output as shown in the Truth Table.

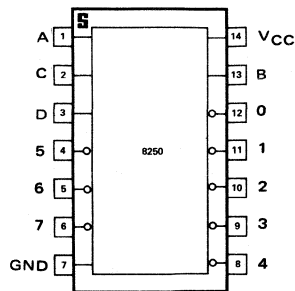
The 8252 is a direct replacement for the 9301 with all outputs being forced high when a binary code greater than nine is applied to the inputs.

The selected output is a logic "0".

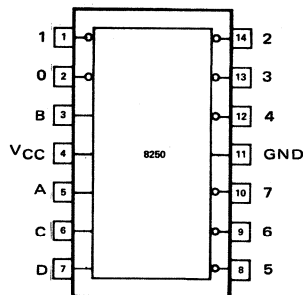
#### TRUTH TABLE

INPUT STATE				OUTPUT STATES											
				8250								8251		8252	
A	B	C	D	0	1	2	3	4	5	6	7	8	9	8	9
0	0	0	0	0	1	1	1	1	1	1	1	1	1	1	1
1	0	0	0	1	0	1	1	1	1	1	1	1	1	1	1
0	1	0	0	1	1	0	1	1	1	1	1	1	1	1	1
1	1	0	0	1	1	1	0	1	1	1	1	1	1	1	1
0	0	1	0	1	1	1	1	0	1	1	1	1	1	1	1
1	0	1	0	1	1	1	1	1	0	1	1	1	1	1	1
0	1	1	0	1	1	1	1	1	0	1	1	1	1	1	1
1	1	1	0	1	1	1	1	1	1	0	1	1	1	1	1
0	0	0	1	1	1	1	1	1	1	1	1	0	1	0	1
1	0	0	1	1	1	1	1	1	1	1	1	1	0	1	0
0	1	0	1	1	1	1	1	1	1	1	1	1	0	1	1
1	1	0	1	1	1	1	1	1	1	1	1	1	1	0	1
0	0	1	1	1	1	1	1	1	1	1	1	1	1	0	1
1	0	1	1	1	1	1	1	1	1	1	1	1	1	1	0
0	1	1	1	1	1	1	1	1	1	1	1	1	1	1	0
1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	0

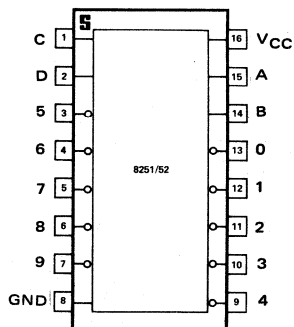
#### A,F PACKAGES



#### W PACKAGE



#### B,F,W PACKAGES



# SIGNETICS BINARY-TO-OCTAL/BCD-TO-DECIMAL DECODER ■ 8250/51/52

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				A	B	C	D	OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS						
"1" Output Voltage	2.6	3.5		V					-800 $\mu$ A	6, 10
"0" Output Voltage			0.4	V					16mA	7, 10
"1" Input Current A, B, C, D			40	$\mu$ A	4.5V	4.5V	4.5V	4.5V		
"0" Input Current A, B, C (8250, 8251)	-0.1		-1.2	mA	0.4V	0.4V	0.4V			
A, B, C, D (8252)	-0.1		-1.6	mA	0.4V	0.4V	0.4V	0.4V		
D (8251 Only)	-0.1		-1.2	mA				0.4V		
D (8250 Only)	-0.1		-1.0	mA				0.4V		

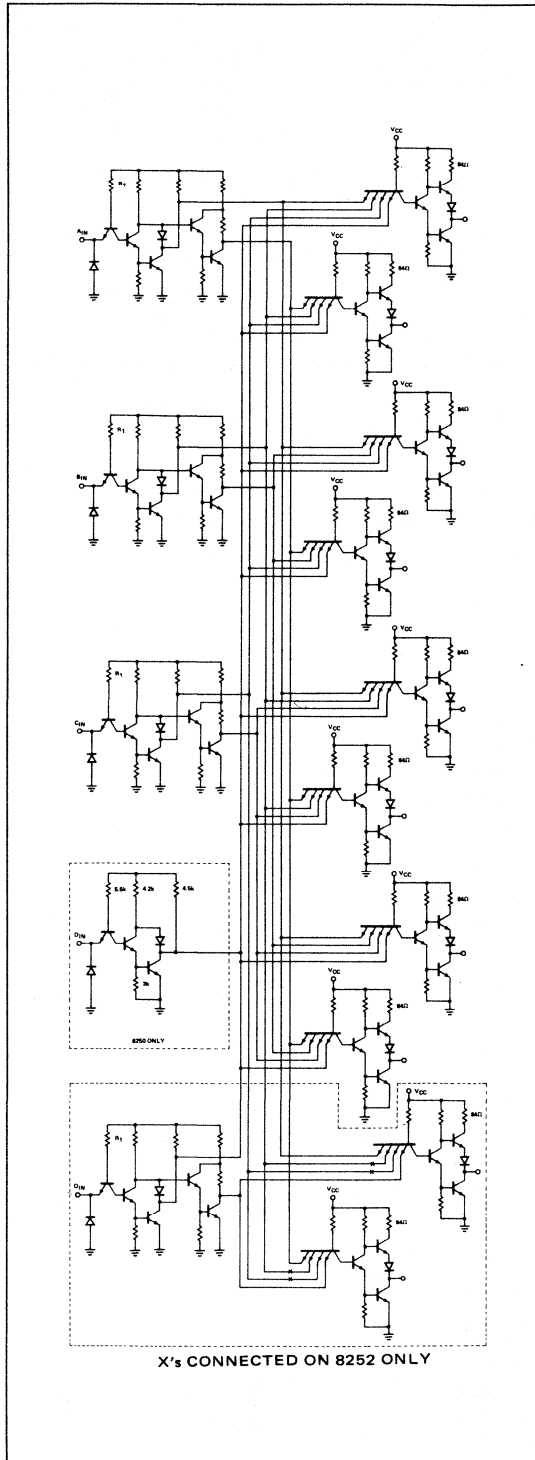
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				A	B	C	D	OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS						
Turn-on Delay $t_{on}$		20	35	ns						8
Turn-off Delay $t_{off}$		20	35	ns						8
Power/Current Consumption (8251 Only)			135/25.7	mW/mA	5.25V	5.25V	5.25V	0V		11
(8250 Only)			125/23.8	mW/mA	5.25V	5.25V	5.25V	0V		11
Input Voltage Rating	5.5			V	10mA	10mA	10mA	10mA		
Output Short Circuit Current										
Outputs 1 thru 9	-10		-55	mA	0V	0V	0V	0V	0V	9, 11
Output 0	-10		-55	mA	5.0V	0V	0V	0V	0V	9, 11

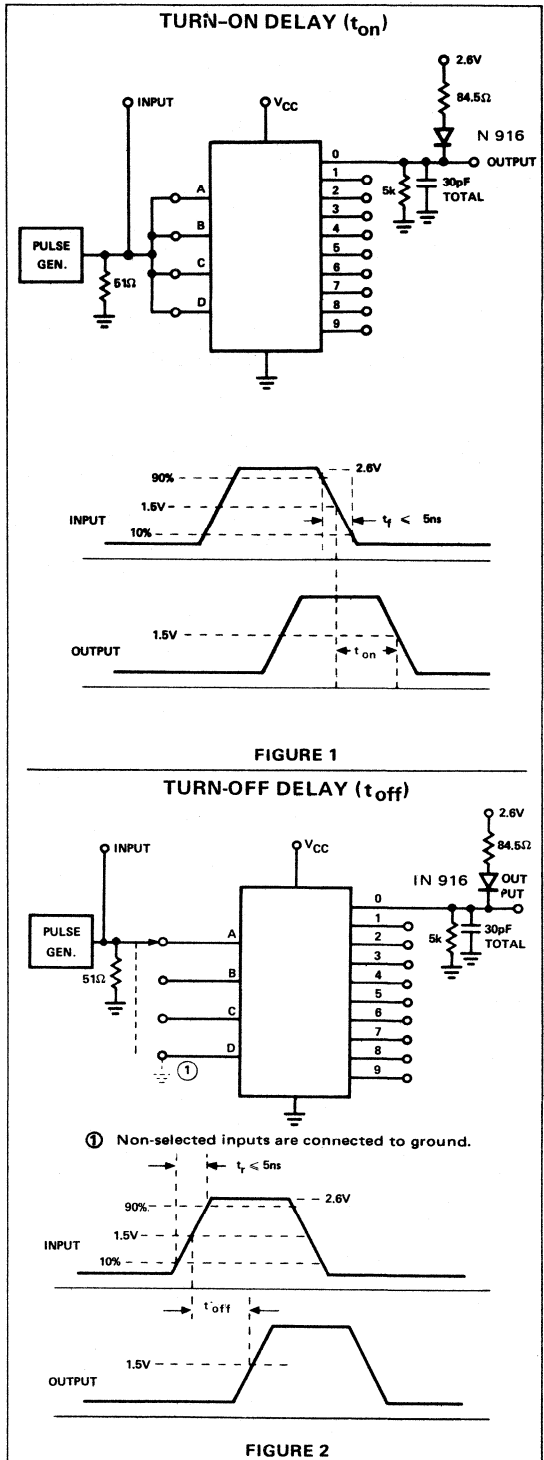
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figures and waveforms.
- Manufacturer reserves the right to make design and process changes and improvements.
- Inputs for "1" and "0" output voltage test is per TRUTH table with threshold levels of 0.8V for logical "0" and 2.0V for logical "1".
- Not more than one output should be shorted at a time.
- $V_{CC} = 5.25$  volts.

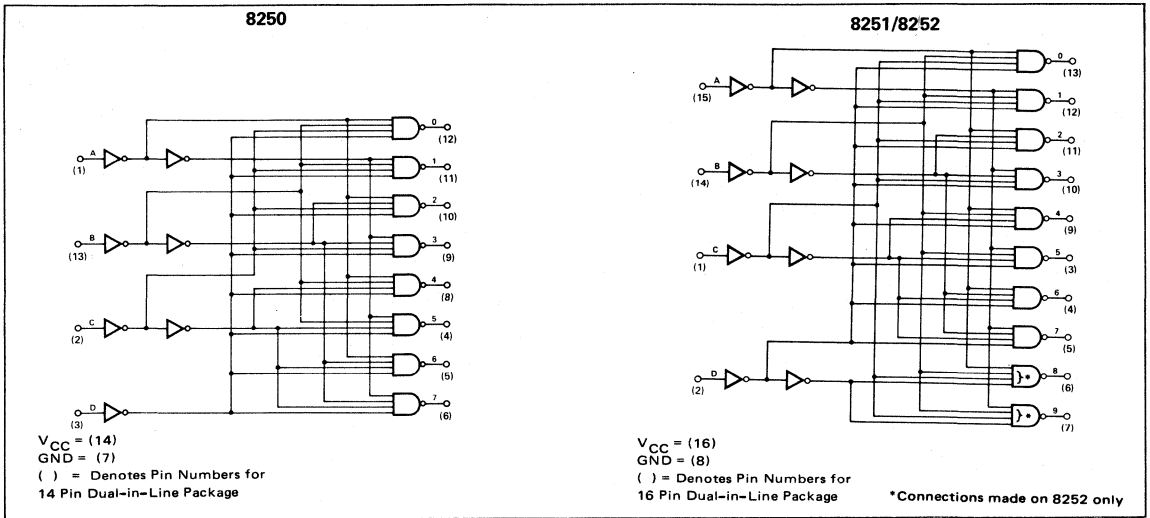
**SCHEMATIC DIAGRAM**



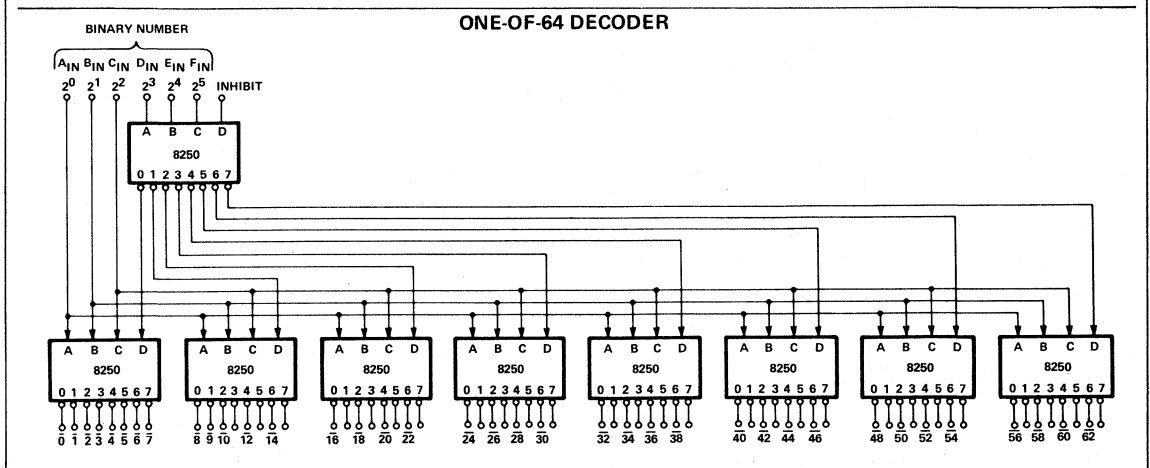
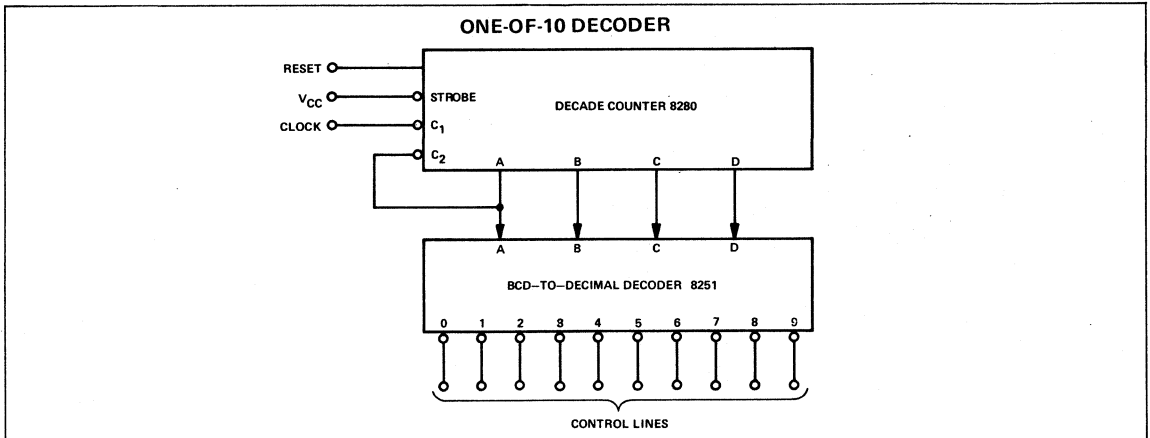
**AC TEST FIGURE AND WAVEFORMS**



LOGIC DIAGRAMS



TYPICAL APPLICATIONS





### DIGITAL 8000 SERIES TTL/MSI

#### DESCRIPTION

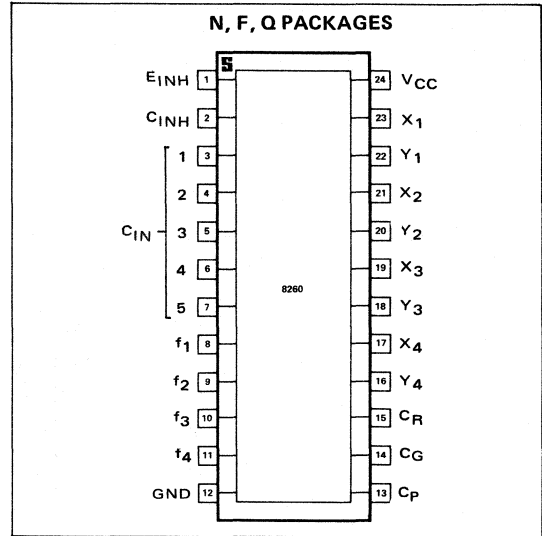
The 8260 Arithmetic Logic Element is a monolithic gate array incorporating four full-adders structured in a look-ahead mode. The device may be used as four mutually independent exclusive NOR or AND gates by proper addressing of the inhibit lines.

As a four-bit adder, the 8260 permits high speed parallel addition of four sets of data and features both simultaneous addition on a character to character and on a bit to bit basis within the package.

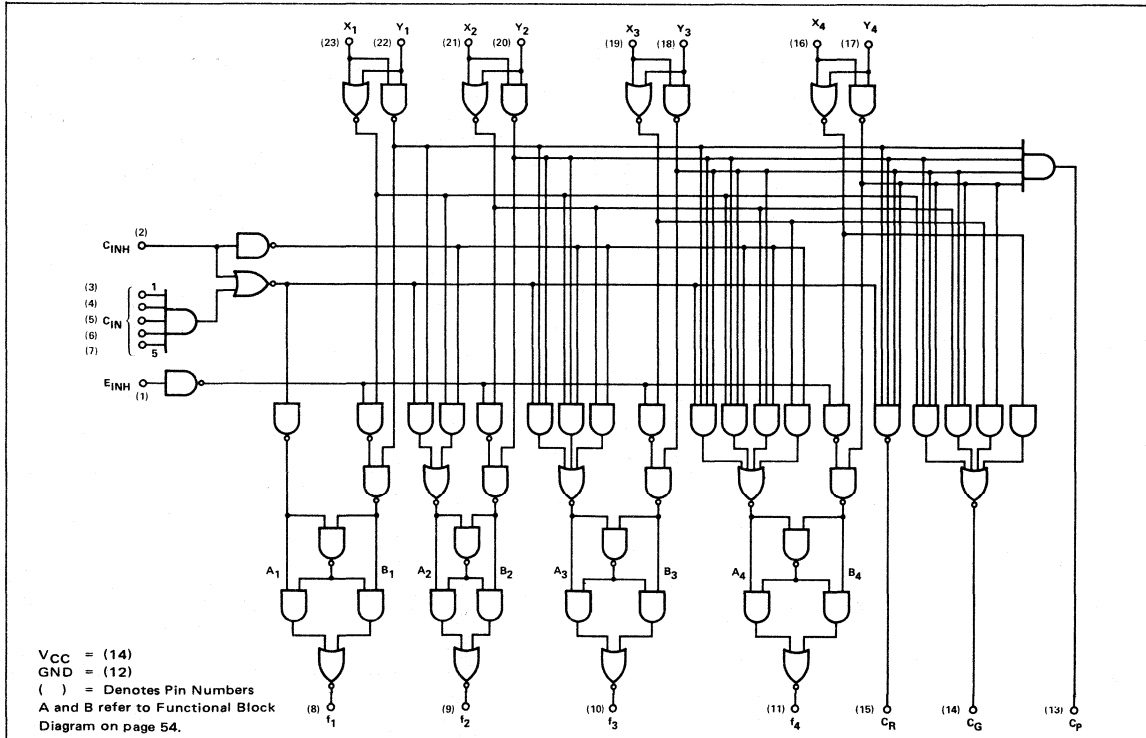
When true input variables are used, the true sum is formed at the f output. Inverted input variables produce the complement of the sum of the true variables.

The carry-outs available are: Internally Generated ( $C_G$ ); Propagated ( $C_P$ ); and Ripple ( $C_R$ ). This gives the 8260 complete flexibility when used in Ripple Carry or Anticipated Carry Adder Systems.

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM



**SIGNETICS ARITHMETIC LOGIC ELEMENT ■ 8260**

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					OUTPUT TERMINALS				NOTES
					INPUT TERMINALS									
	MIN.	TYP.	MAX.	UNITS	X <sub>n</sub>	Y <sub>n</sub>	C <sub>IN</sub>	C <sub>INH</sub>	E <sub>INH</sub>	C <sub>p</sub>	C <sub>G</sub>	C <sub>R</sub>	f <sub>n</sub>	
"1" Output Voltage	2.6	3.5		V	2.0	2.0	2.0	2.0	2.0		-800 μA	-800 μA	-800 μA	1
"0" Output Voltage														
f <sub>n</sub> , C <sub>G</sub> and C <sub>R</sub> C <sub>p</sub>			0.4 0.4	V	0.8 2.0	0.8 2.0	0.8 2.0	0.8 2.0	0.8 2.0	16 mA	9.6 mA	9.6 mA	9.6 mA	2 2
X <sub>n</sub> and C <sub>INH</sub>	-0.1		-3.2	mA	0.4	5.25		0.4						
Y <sub>n</sub>	-0.1		-3.2	mA	5.25	0.4								
E <sub>INH</sub> & C <sub>IN1</sub> , through C <sub>IN5</sub>	-0.1		-1.6	mA			0.4		0.4					3
"1" Input Current														
X <sub>n</sub> and C <sub>INH</sub>			80	μA	4.5	0V		4.5						
Y <sub>n</sub>			80	μA	0V	4.5								
E <sub>INH</sub> & C <sub>IN1</sub> , through C <sub>IN5</sub>			40	μA			4.5		4.5					4
Input Voltage Rating														
X <sub>n</sub> and C <sub>INH</sub>	5.5			V	10mA	0V		10mA						
Y <sub>n</sub>	5.5			V	0V	10mA								
E <sub>INH</sub> & C <sub>IN1</sub> , through C <sub>IN5</sub>	5.5			V			10mA		10mA					4
Power/Current Consumption			400/ 76.2	600/ 114.1	mW/ mA									11

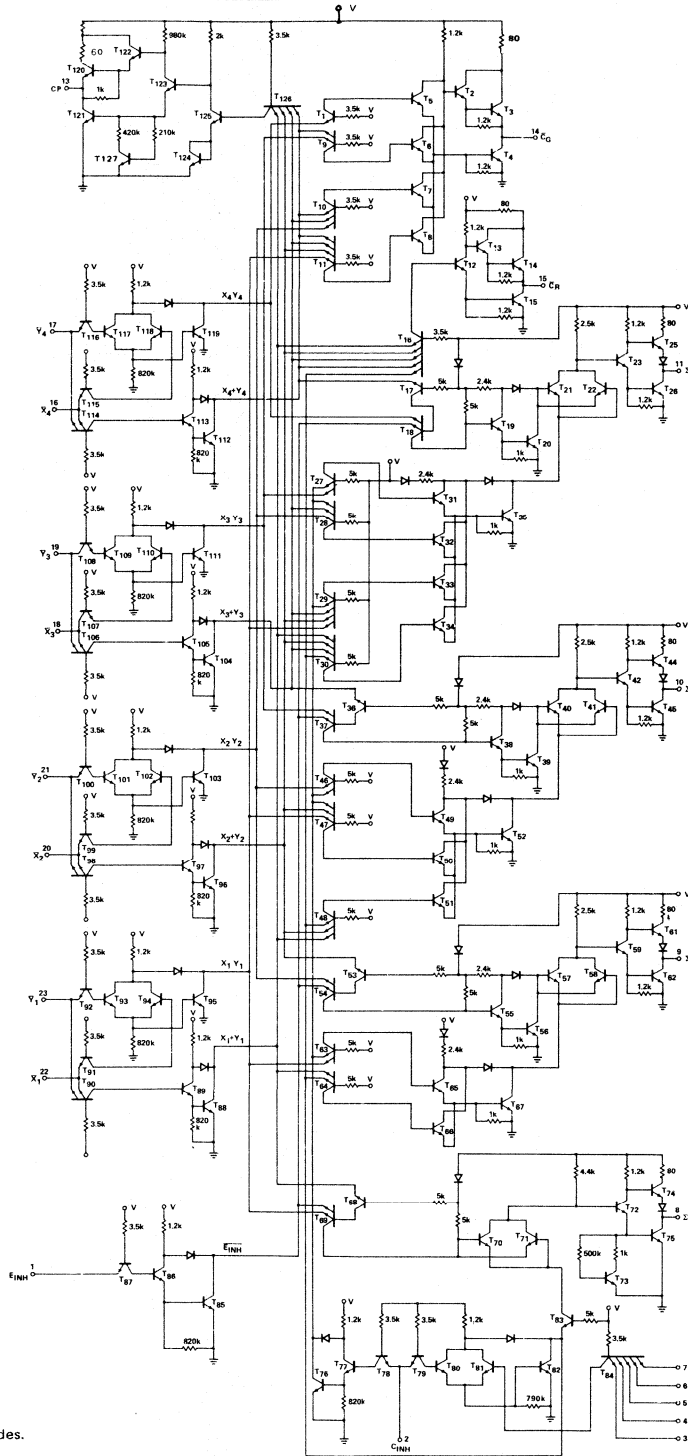
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS					OUTPUT TERMINALS				NOTES
					INPUT TERMINALS									
	MIN.	TYP.	MAX.	UNITS	X <sub>n</sub>	Y <sub>n</sub>	C <sub>IN</sub>	C <sub>INH</sub>	E <sub>INH</sub>	C <sub>p</sub>	C <sub>G</sub>	C <sub>R</sub>	f <sub>n</sub>	
Propagation Delay														
X <sub>n</sub> , Y <sub>n</sub> and C <sub>IN</sub> to C <sub>R</sub>		14	20	ns										12
X <sub>n</sub> and Y <sub>n</sub> to C <sub>p</sub> and C <sub>G</sub>		14	20	ns										12
X <sub>n</sub> and Y <sub>n</sub> to f <sub>n</sub>		24	33	ns										12
C <sub>IN</sub> to f <sub>n</sub>		14	22	ns										12
Output Short Circuit Current														
f <sub>n</sub> , C <sub>G</sub> and C <sub>R</sub>	-20		-70	mA	5.0	5.0	5.0	5.0	5.0		0V	0V	0V	10, 11
C <sub>p</sub>	-30		-90	mA	0V					0V				10, 11

**NOTES**

- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- When testing for separate C<sub>IN</sub> inputs, tie the remaining C<sub>IN</sub> inputs to V<sub>CC</sub>.
- When testing for separate C<sub>IN</sub> inputs, tie the remaining C<sub>IN</sub> inputs to ground.
- Keep unused inputs tied to V<sub>CC</sub> unless otherwise specified.
- All voltage measurements are referenced to the ground terminal.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Not more than one output should be shorted at a time.
- V<sub>CC</sub> = 5.25V.
- Refer to AC test figure and waveforms.

SCHEMATIC DIAGRAM



8260 - 4 BIT ADDER  
 V<sub>CC</sub> = Pin 24  
 GND = Pin 12  
 All inputs have clamp diodes.

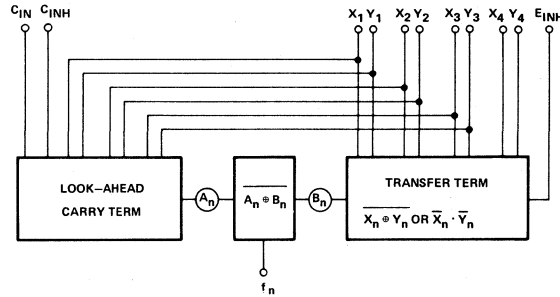
C<sub>1N5</sub>  
 C<sub>1N4</sub>  
 C<sub>1N3</sub>  
 C<sub>1N2</sub>  
 C<sub>1N1</sub>

MODE OF OPERATION

INPUTS	Least Significant C <sub>IN</sub> Inputs to be *	CONTROLS		f	
		C <sub>INH</sub>	E <sub>INH</sub>		
X <sub>n</sub> ' Y <sub>n</sub> ↓	0	0	0	Σ <sub>n</sub>	Add
	0	0	1	--	Not Used
	0	1	0	X <sub>n</sub> Y <sub>n</sub> +X <sub>n</sub> Y <sub>n</sub>	Coincidence
	0	1	1	X <sub>n</sub> Y <sub>n</sub>	AND
X <sub>n</sub> ' Y <sub>n</sub> ↓	1	0	0	Σ <sub>n</sub>	Add
	1	0	1	---	Not Used
	1	1	0	X <sub>n</sub> Y <sub>n</sub> +X <sub>n</sub> Y <sub>n</sub>	Coincidence
	1	1	1	X <sub>n</sub> Y <sub>n</sub>	AND

\* Least significant of a "Multiple Package" adder system.

FUNCTIONAL BLOCK DIAGRAM



TRUTH TABLES

C<sub>INH</sub> = 1 → A<sub>n</sub> = 1  
 C<sub>INH</sub> = 0 → A<sub>n</sub> = 0

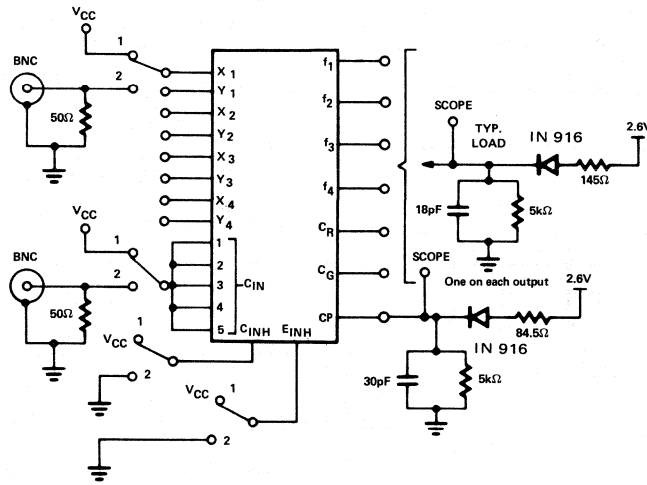
C <sub>IN</sub>	A <sub>1</sub>	A <sub>1</sub>	X <sub>1</sub>	Y <sub>1</sub>	A <sub>2</sub>	A <sub>2</sub>	X <sub>2</sub>	Y <sub>2</sub>	A <sub>3</sub>	A <sub>3</sub>	X <sub>3</sub>	Y <sub>3</sub>	A <sub>4</sub>
0	0	0	0	0	0	0	0	0	0	0	0	0	0
1	1	0	0	1	0	0	0	1	0	0	0	1	0
	0	1	0	0	0	0	1	0	0	0	1	0	0
	0	1	1	1	0	1	1	1	0	1	1	1	1
	1	0	0	0	1	0	0	0	1	0	0	0	0
	1	0	1	1	1	1	0	1	1	0	1	1	1
	1	1	0	1	1	1	1	0	1	1	1	0	1
	1	1	1	1	1	1	1	1	1	1	1	1	1
	1	1	1	1	1	1	1	1	1	1	1	1	1

A <sub>n</sub>	B <sub>n</sub>	f <sub>n</sub>
0	0	1
0	1	0
0	1	0
0	1	1
1	0	0
1	0	0
1	1	1

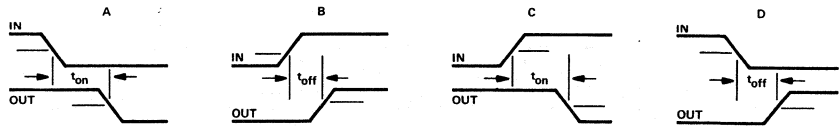
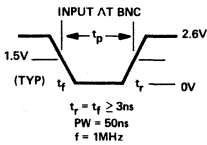
  

E <sub>INH</sub>	X <sub>n</sub>	Y <sub>n</sub>	B <sub>n</sub>
0	0	0	1
0	0	1	0
0	1	0	0
0	1	1	1
1	0	0	0
1	0	1	0
1	1	0	0
1	1	1	1

AC TEST FIGURE AND WAVEFORMS



NOTE: Scope terminals to be  $\leq 1/8''$  from Package Pins.



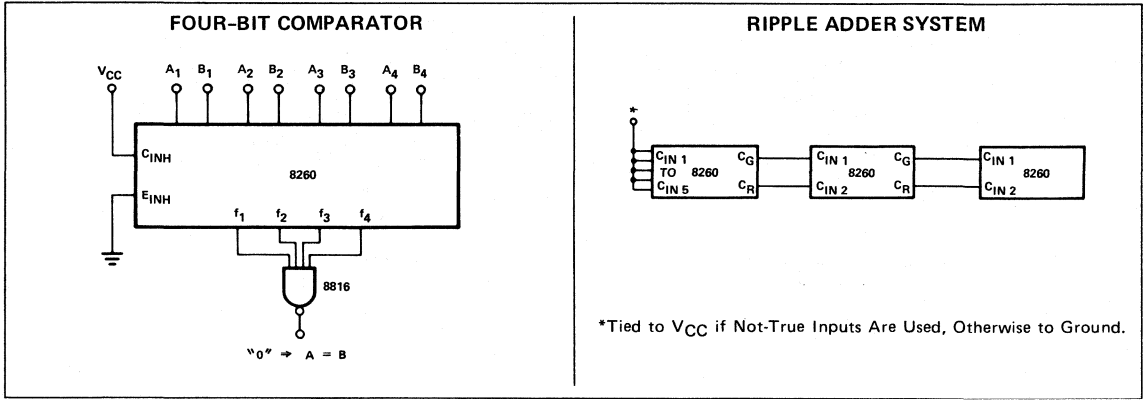
STEP NO.	DELAY FROM-TO	SWITCH POSITION											WAVEFORM TYPE			
		DRIVEN INPUTS	OTHER INPUTS													
			X <sub>1</sub>	Y <sub>1</sub>	X <sub>2</sub>	Y <sub>2</sub>	X <sub>3</sub>	Y <sub>3</sub>	X <sub>4</sub>	Y <sub>4</sub>	C <sub>IN</sub>	E <sub>INH</sub>		C <sub>INH</sub>		
1	X <sub>n</sub> to C <sub>R</sub> or X <sub>n</sub> to C <sub>p</sub>	2	2	1	2	1	2	1	2	1	2	1	2	2	2	A, B C, D
2	Y <sub>n</sub> to C <sub>R</sub> or Y <sub>n</sub> to C <sub>p</sub>	2	1	2	1	2	1	2	1	2	2	2	2	2	2	A, B C, D
3	X <sub>n</sub> , Y <sub>n</sub> to f <sub>n</sub>	2	1	1	1	1	1	1	1	1	1	1	1	1	1	A, B
4	C <sub>IN</sub> to C <sub>R</sub>	2	2	2	2	2	2	2	2	2	2	2	2	2	2	A, B
5	C <sub>IN</sub> to f <sub>n</sub>	2	1	2	1	2	1	2	1	2	2	2	2	2	2	C, D

**TYPICAL APPLICATIONS**

The 8260 contains the control logic necessary to allow operation as a general purpose arithmetic logic device. Below, the internal carries are inhibited to effect Exclusive-NOR or coincidence operation. The 8260 may also be operated as four independent

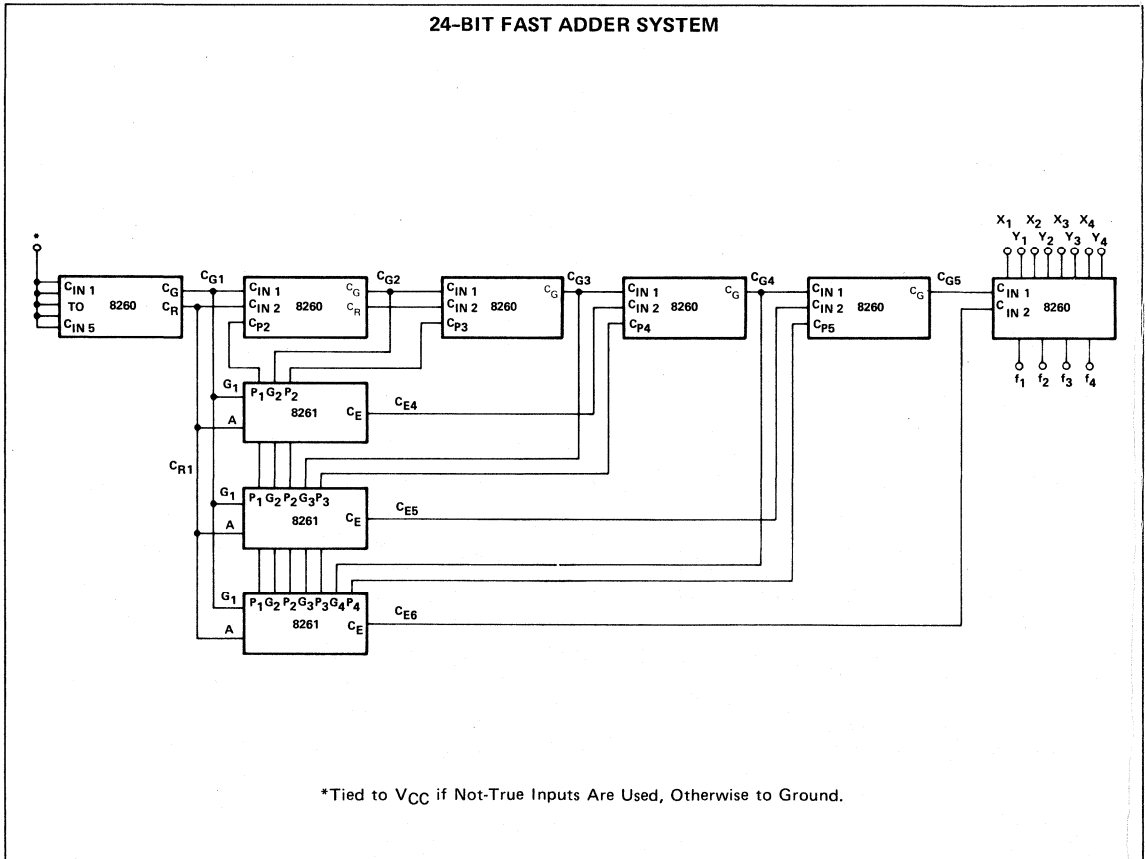
AND gates to implement masking and similar requirements of micro-programming.

The Ripple Adder System is the simplest but also the slowest application of the 8260. The typical total addition time (input to sum output for 12-bit ripple adder is 42ns).



The Fast Adder System provides complete carry look-ahead addition for words to 24 bits in length and is the fastest application of

the 8260 units. The typical total addition time for a 24 bit fast adder is 42ns.

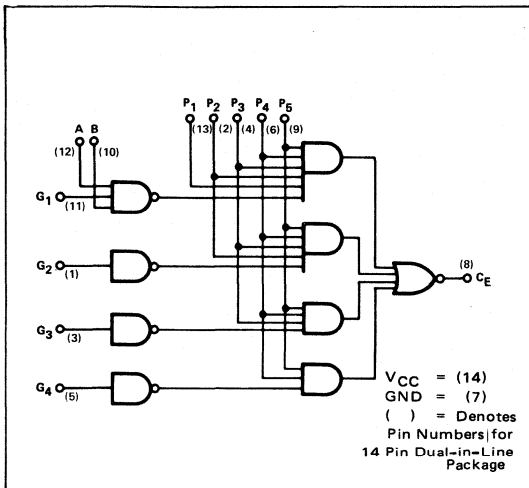


### DIGITAL 8000 SERIES TTL/MSI

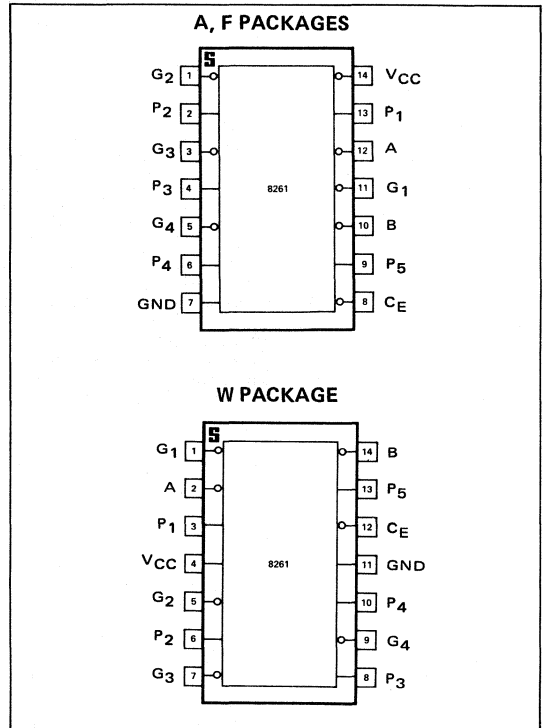
#### DESCRIPTION

The 8261 Fast Carry Extender is a monolithic gate array designed specifically to be used in conjunction with the 8260 Arithmetic Logic element. A 8260/8261 combination facilitates the implementation of the look-ahead technique in adder systems, thus considerably improving propagation times. The circuit structure of this array is of the familiar TTL type.

#### LOGIC DIAGRAM



#### PIN CONFIGURATIONS (Top View)



#### ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
					DRIVEN INPUTS		OTHER INPUTS			
	MIN.	TYP.	MAX.	UNITS	G,A,B	P	G,A,B	P		
"1" Output Voltage	2.6	3.5		V	2.0V				-800μA	6
"0" Output Voltage			0.4	V	0.8V		4.75V	4.75V	9.6mA	7
"1" Input Current										
G Input			40	μA	4.5V		A = 0V			
A and B Inputs			40	μA	4.5V		G <sub>1</sub> = 0V			
P <sub>1</sub> Input			40	μA		4.5V		0V		
P <sub>2</sub> Input			80	μA		4.5V		0V		
P <sub>3</sub> Input			120	μA		4.5V		0V		
P <sub>4</sub> and P <sub>5</sub> Inputs			160	μA		4.5V		0V		
"0" Input Current										
G, A and B			-1.6	mA	0.4V			5.25V		
P <sub>1</sub> Input			-1.6	mA		0.4V	0V	5.25V		
P <sub>2</sub> Input			-3.2	mA		0.4V	0V	5.25V		
P <sub>3</sub> Input			-4.8	mA		0.4V	0V	5.25V		
P <sub>4</sub> and P <sub>5</sub> Inputs			-6.4	mA		0.4V	0V	5.25V		
Power/Current Consumption		115/22	158/30	mW/mA			5.25V	0V		10
Input Voltage Rating	5.5			V	10mA	10mA	0V	0V		

**SIGNETICS FAST CARRY EXTENDER ■ 8261**

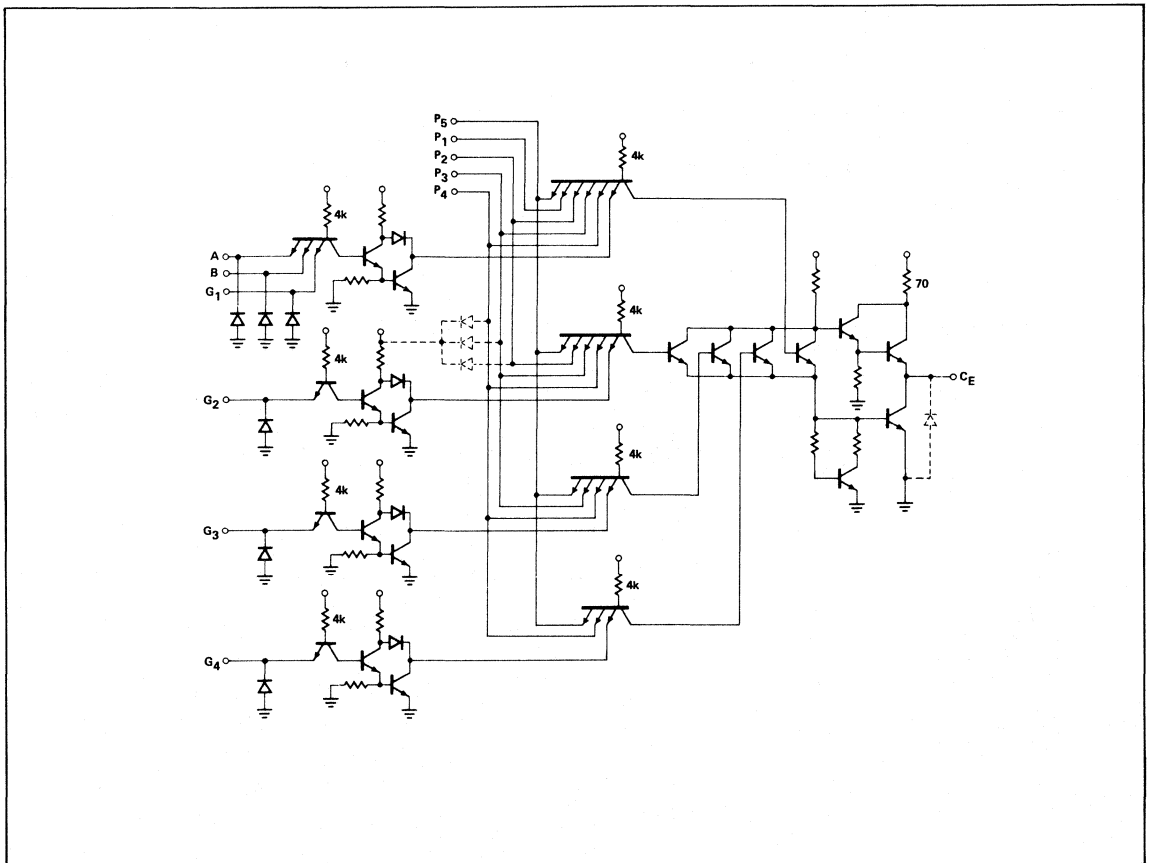
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
					DRIVEN INPUTS		OTHER INPUTS			
	MIN.	TYP.	MAX.	UNITS	G,A,B	P	G,A,B	P		
Turn-on Delay, $t_{on}$ G to $C_E$		16	25	ns						8
P to $C_E$		13	25	ns						8
Turn-off Delay, $t_{off}$ G to $C_E$		16	23	ns						8
P to $C_E$		9	15	ns						8
Output Short Circuit Current	-20		-70	mA	5.0V	0V			0V	10

**NOTES**

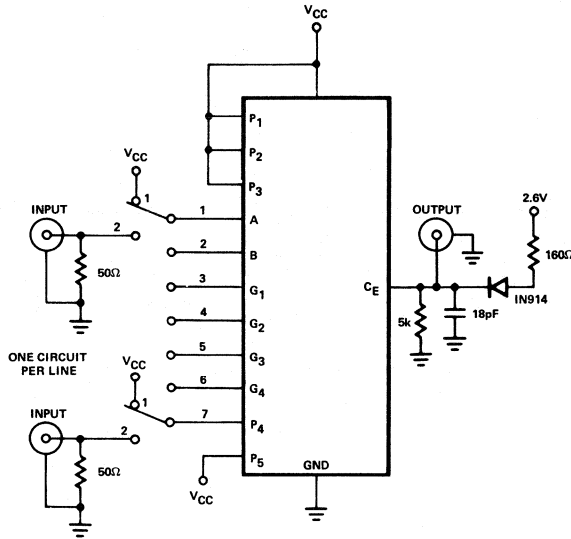
- All voltage and current measurements are referenced to the ground terminal. Input terminals not specifically referenced are tied to  $V_{CC}$ .
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figure.
- Input "0" thresholds for  $P_1$  through  $P_5$  inputs are guaranteed to be 0.7 volts.
- $V_{CC} = 5.25\text{V}$ .

**SCHEMATIC DIAGRAM**



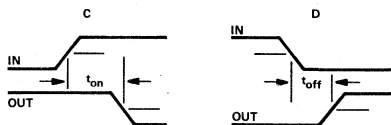
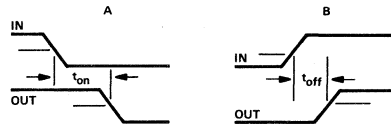
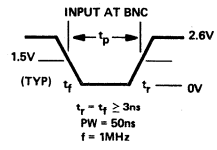


AC TEST FIGURE AND WAVEFORMS



TEST TABLE

PIN DESIGNATION	INPUT							WAVEFORM
	A	B	G <sub>1</sub>	G <sub>2</sub>	G <sub>3</sub>	G <sub>4</sub>	P <sub>4</sub>	
1	PULSE	1	1	1	1	1	1	A,B
2	1	PULSE	1	1	1	1	1	
3	1	1	PULSE	1	1	1	1	
4	1	1	1	PULSE	1	1	1	
5	1	1	1	1	PULSE	1	1	
6	1	1	1	1	1	PULSE	1	
7	2	2	2	2	2	2	PULSE	

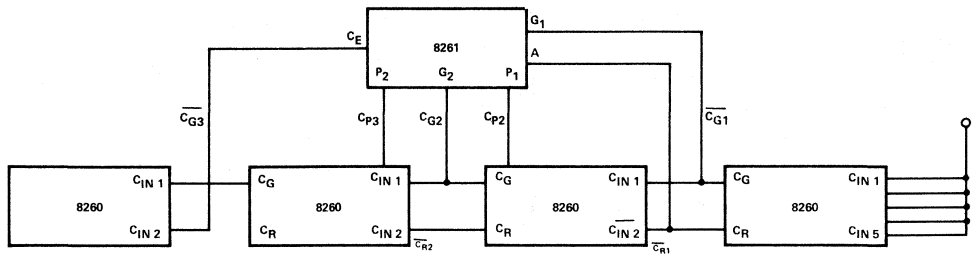


NOTES:

- A. Position 1 on all switches provides a logical "1". Position 2 on all switches provides a logical "0" when input signal is not present.
- B. All measurements are made at 1.5 volts level.

# SIGNETICS FAST CARRY EXTENDER ■ 8261

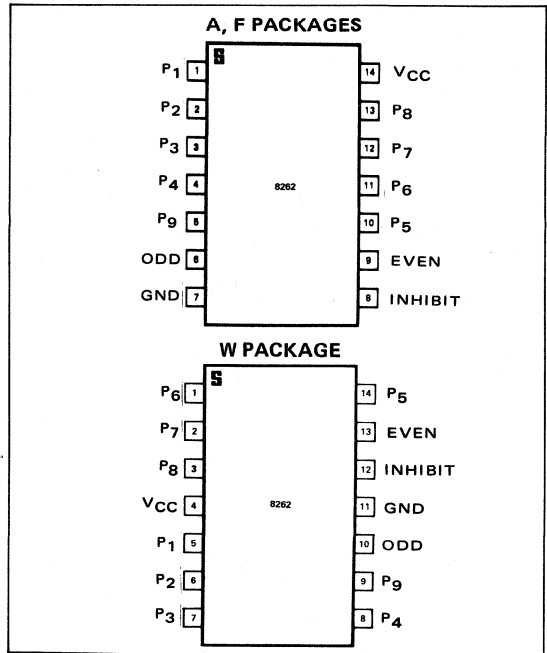
## TYPICAL APPLICATION



16 BIT,  $T_A = 42ns$ , typical Fast Adder System (5 packages)  
 \*Tied to  $V_{CC}$  if not-true inputs are used, otherwise to ground. Unused 8261 pins should be tied to  $V_{CC}$ .

DIGITAL 8000 SERIES TTL/MSI

PIN CONFIGURATIONS (Top View)



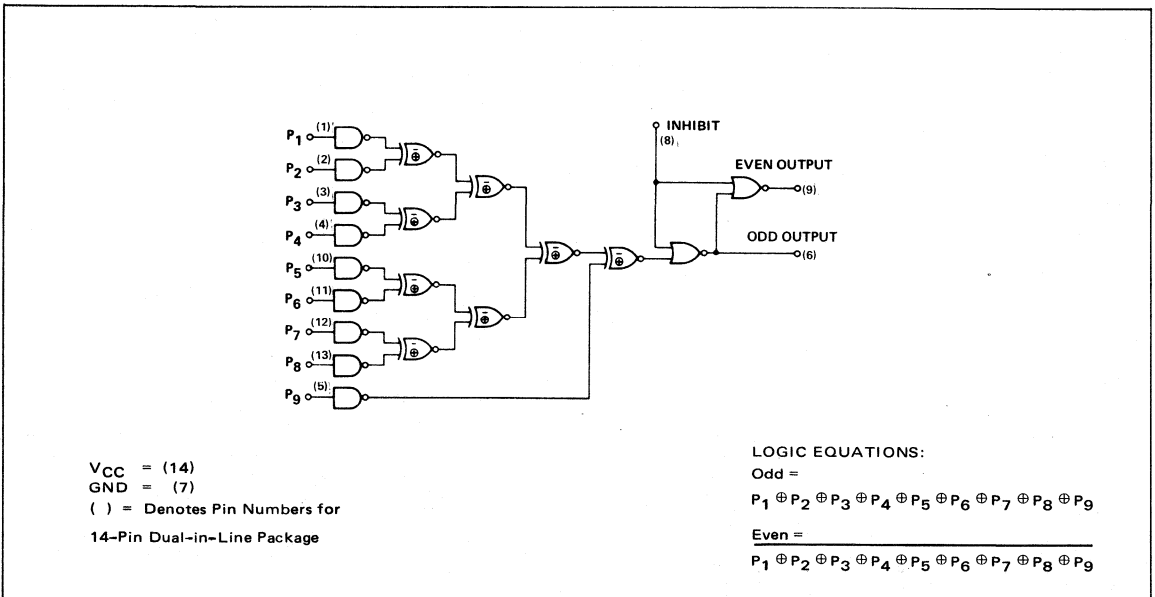
### DESCRIPTION

The 8262 9-Input Parity Generator/Parity Checker is a versatile MSI device commonly used to detect errors in data transmission or in data retrieval. Two outputs (EVEN and ODD) are provided for versatility. An INHIBIT input is provided to disable both outputs of the 8262. (A logic 1 on the INHIBIT input forces both outputs to a logic 0).

When used as a Parity Generator, the 8262 supplies a parity bit which is transmitted together with the data word.

At the receiving end, the 8262 acts as a Parity Checker and indicates that data has been received correctly or that an error has been detected.

### LOGIC DIAGRAM



# SIGNETICS 9-BIT PARITY GENERATOR AND CHECKER ■ 8262

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS	INHIBIT	OUTPUTS UNDER TEST	NOTES
	MIN.	TYP.	MAX.	UNITS	DATA INPUT UNDER TEST			
"1" Output Voltage								
Even	2.6	3.5		V	0V	.8V	-800 $\mu$ A	6
Odd	2.6	3.5		V	2.0V	.8V	-800 $\mu$ A	6
"0" Output Voltage								
Even			0.40	V	2.0V	.8V	16mA	7
Odd			0.40	V	0V	.8V	16mA	7
"0" Input Current								
Data Inputs	-0.1		-1.6	mA	0.4V			
Inhibit	-0.1		-3.2	mA		0.4V		
"1" Input Current								
Data Inputs			80	$\mu$ A	4.5V			
Inhibit			160	$\mu$ A		4.5V		
Input Voltage Rating								
Data Inputs	5.5			V	10mA			
Inhibit	5.5			V		10mA		
Power/Current Consumption		300/57	370/70	mW/mA				9
Output Short Circuit Current								
Even	-20		-70	mA	0V	0V	0V	9, 10
Odd	-20		-70	mA	4.5V	0V	0V	9, 10

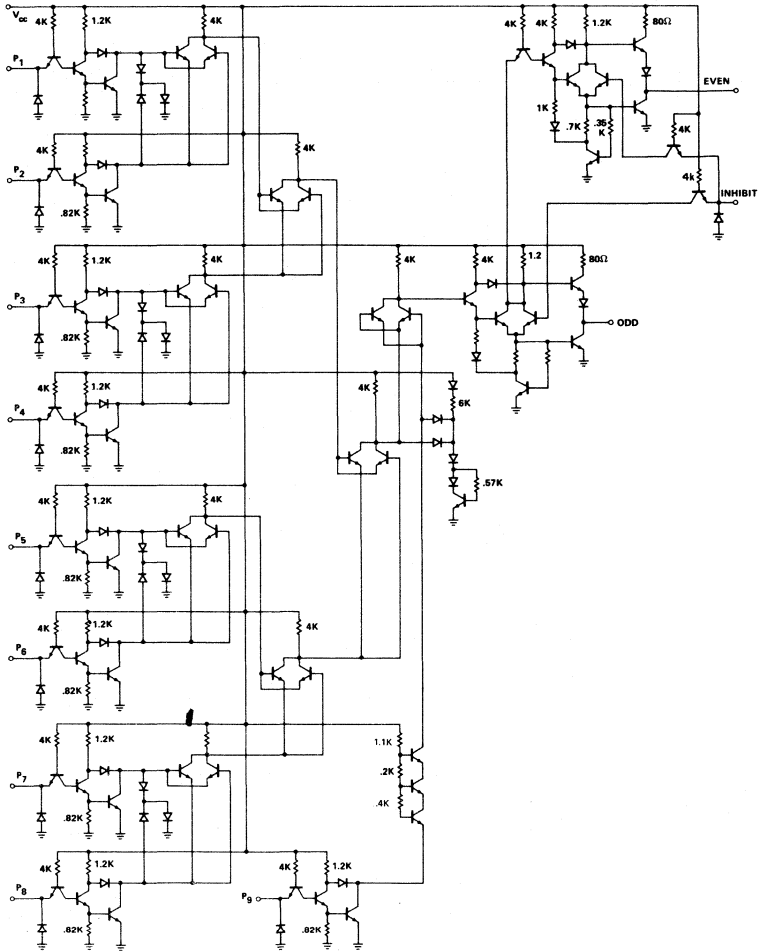
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	INHIBIT	OUTPUTS UNDER TEST	NOTES
	MIN.	TYP.	MAX.	UNITS	UNDER TEST			
Turn-On Times								
$P_1 - P_8$ to Even		35	50	ns	Pulse			8
$P_1 - P_8$ to Odd		30	45	ns	Pulse			8
$P_9$ to Even		20	35	ns	Pulse			8
$P_9$ to Odd		15	30	ns	Pulse			8
Inhibit to Even		8	15	ns		Pulse		8
Inhibit to Odd		8	15	ns		Pulse		8
Turn-Off Times								
$P_1 - P_8$ to Even		38	55	ns	Pulse			8
$P_1 - P_8$ to Odd		32	45	ns	Pulse			8
$P_9$ to Even		23	40	ns	Pulse			8
$P_9$ to Odd		20	35	ns	Pulse			8
Inhibit to Even		10	18	ns		Pulse		8
Inhibit to Odd		10	18	ns		Pulse		8

### NOTES

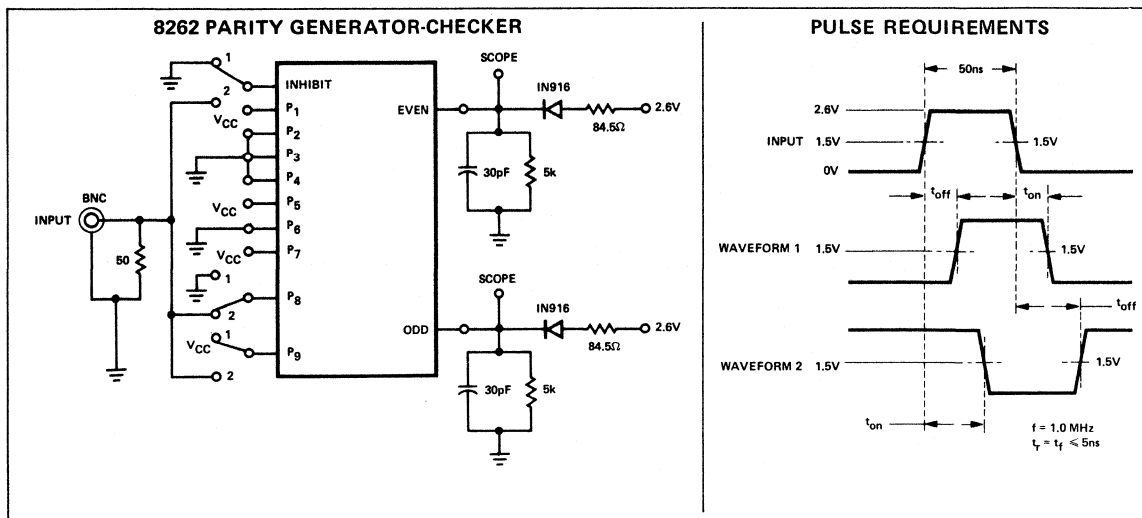
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figure.
- $V_{CC} = 5.25$  volts.
- Not more than one output should be shorted at a time.

SCHEMATIC DIAGRAM



# SIGNETICS 9-BIT PARITY GENERATOR AND CHECKER ■ 8262

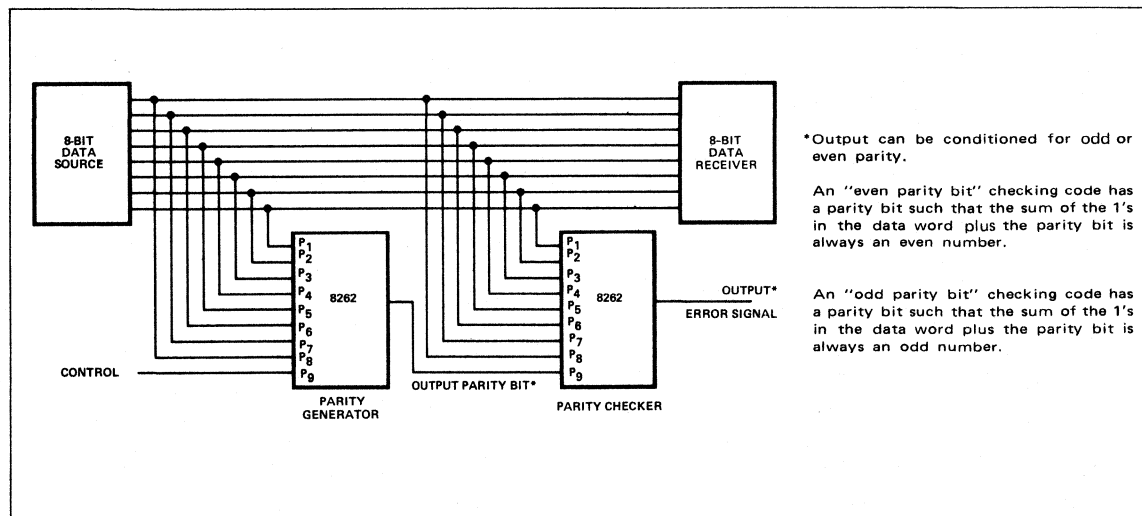
## AC TEST FIGURE AND WAVEFORMS



## TRUTH TABLE

MEASURE DELAY FROM	SWITCH POSITION			WAVEFORM	
	INH	P <sub>8</sub>	P <sub>9</sub>	EVEN	ODD
P <sub>8</sub> to ODD	1	2	1		1
P <sub>9</sub> to ODD	1	1	2		2
P <sub>8</sub> to EVEN	1	2	1	2	
P <sub>9</sub> to EVEN	1	1	2	1	
INH to EVEN	2	1	1	2	

## TYPICAL APPLICATIONS



#### DESCRIPTION

The 8263/8264 3-Input, 4-Bit Multiplexer is a gating array whose function is analogous to that of a 4-pole, 3-position switch. Four bits of digital data are selected from one of three inputs. A 2-bit channel-selection code determines which input is to be active.

The Data Complement input controls the conditional complement circuit at the Multiplexer output to effect either inverting or non-inverting data flow.

The 8263 employs active output structures to effect minimum delays: the 8264 utilizes bare collector outputs for expansion of input terms.

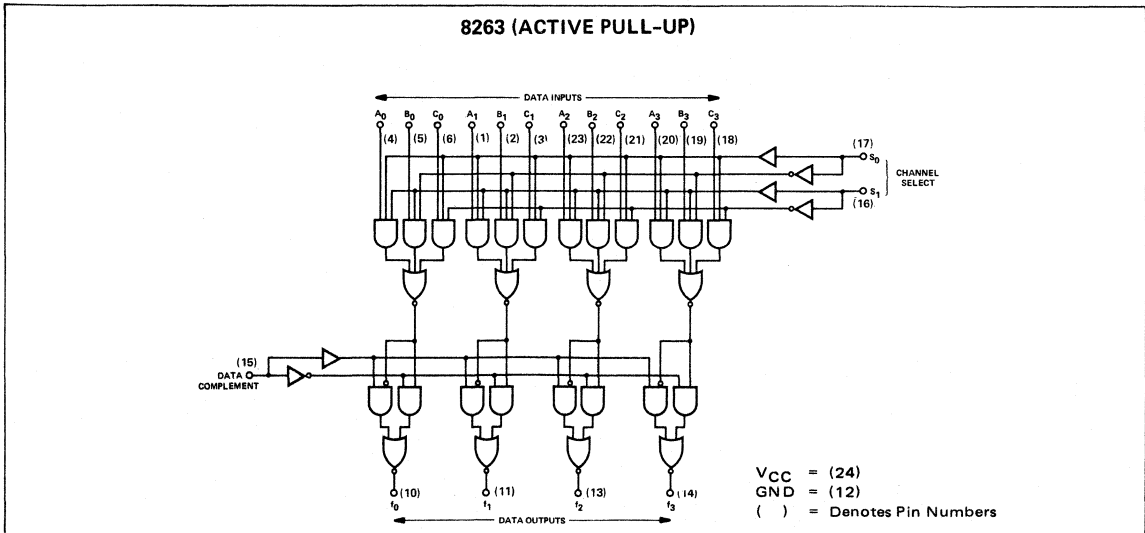
The 8264 may be expanded by connecting its outputs to the outputs of another 8264. Provision is made for use of a 3-bit code to determine which Multiplexer is selected; thus, eight Multiplexers may be commoned to effect a 4-pole, 24-position switch.

#### TRUTH TABLE

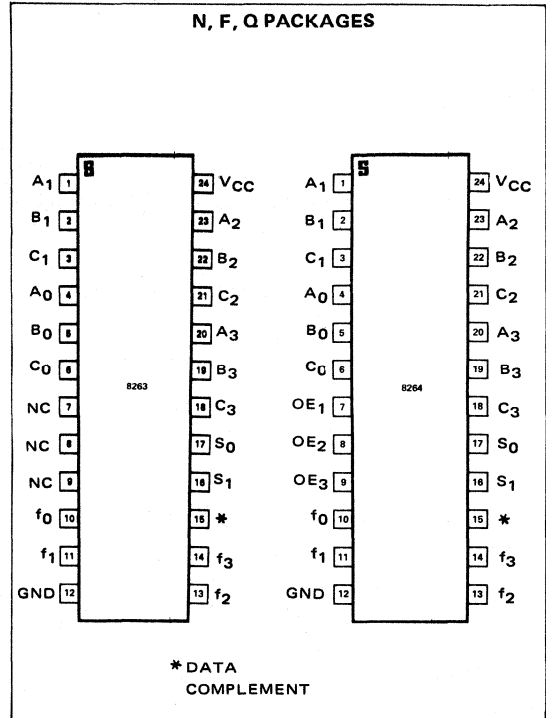
Data Input	Channel Select	Data Complement	Output Enable (8264)	Data Outputs
$A_n B_n C_n$	$S_0 S_1$			
$A_n$ x x	1 1	0	1	$A_n$
x $B_n$ x	0 1	0	1	$B_n$
x x $C_n$	1 0	0	1	$C_n$
x x x	0 0	0	1	0
$A_n$ x x	1 1	1	1	$\bar{A}_n$
x $B_n$ x	0 1	1	1	$\bar{B}_n$
x x $C_n$	1 0	1	1	$\bar{C}_n$
x x x	0 0	1	1	1
x x x	x x	x	0	1

X = Either State

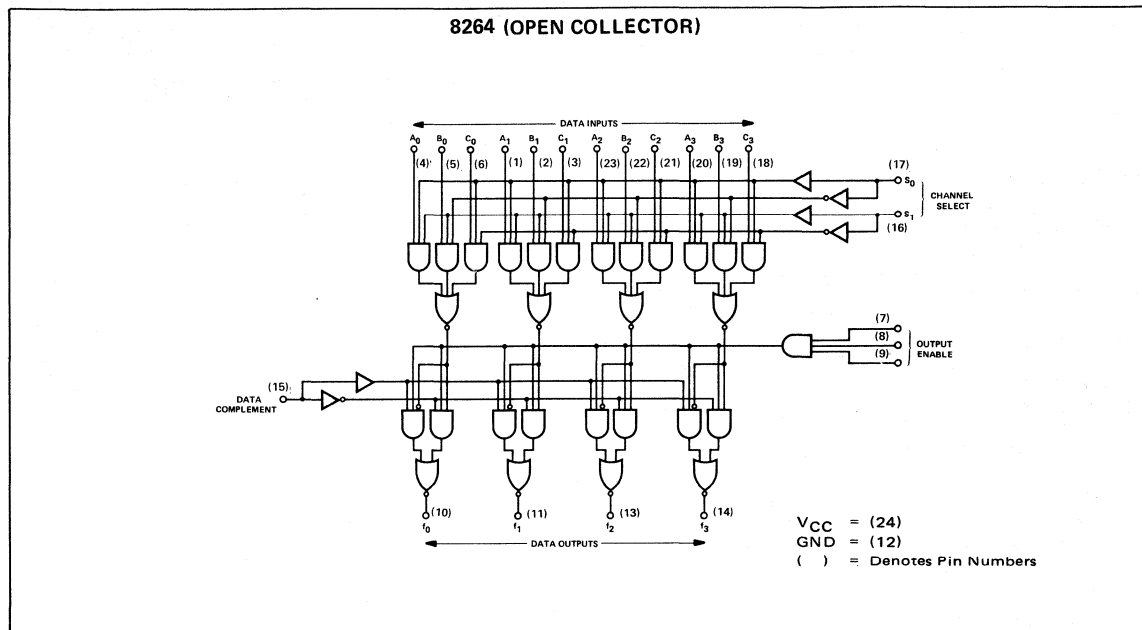
#### LOGIC DIAGRAM



#### PIN CONFIGURATIONS (Top View)



LOGIC DIAGRAMS (Cont'd)



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS								NOTES
	MIN.	TYP.	MAX.	UNITS	$A_n$	$B_n$	$C_n$	$S_0$	$S_1$	DATA COMP	OUTPUT ENABLE	OUTPUTS	
"1" Output Voltage (8263)	2.6	3.5		V	2.0V	2.0V	2.0V	2.0V	2.0V	0.8V		-800 $\mu$ A	6
"1" Output Leakage Current (8264)			200	$\mu$ A	2.0V	2.0V	2.0V	2.0V	2.0V	0.8V	2.0V		8
"0" Output Voltage (8263)			0.4	V	0.8V	0.8V	0.8V	2.0V	2.0V	0.8V		9.6mA	7
"0" Output Voltage (8264)			0.4	V	0.8V							16.0mA	7
"0" Input Current													
$A_n$	-0.1		-1.6	mA	0.4V								
$B_n$	-0.1		-1.6	mA		0.4V		0.4V					
$C_n$	-0.1		-1.6	mA			0.4V		0.4V				
OE, DC	-0.1		-1.6	mA						0.4V	0.4V		
$S_0, S_1$	-0.1		-3.2	mA				0.4V	0.4V				
"1" Input Current													
$A_n$			40	$\mu$ A	4.5V			0V	0V				
$B_n$			40	$\mu$ A		4.5V		0V	0V				
$C_n$			40	$\mu$ A			4.5V	0V					
OE, DC			40	$\mu$ A						4.5V	4.5V		
$S_0, S_1$			80	$\mu$ A				4.5V	4.5V				

NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic Definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Connect an external 1k  $\pm$ 1% resistor from  $V_{CC}$  to the output for this test.
- $V_{CC} = 5.25V$ .
- Refer to AC test figure.
- Not more than one output should be shorted at a time.



T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS									NOTES
	MIN.	TYP.	MAX.	UNITS	A <sub>n</sub>	B <sub>n</sub>	C <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	DATA COMP	OUTPUT ENABLE	OUTPUTS		
Propagation Delay (8263)														
A <sub>n</sub> to f <sub>n</sub>		17	26	ns										10
S <sub>0</sub> , S <sub>1</sub> to f <sub>n</sub>		25	36	ns										10
DC to f <sub>n</sub>		17	26	ns										10
Propagation Delay (8264)														
A <sub>n</sub> to f <sub>n</sub>		25	36	ns										10
S <sub>0</sub> , S <sub>1</sub> to f <sub>n</sub>		25	36	ns										10
DC to f <sub>n</sub>		20	30	ns										10
OE to f <sub>n</sub>		20	30	ns										10
Input Voltage Rating														
A <sub>n</sub>	5.5			V	10mA			0V	0V					
B <sub>n</sub>	5.5			V		10mA		0V	0V					
C <sub>n</sub>	5.5			V			10mA	0V	0V					
S <sub>0</sub>	5.5			V				10mA						
S <sub>1</sub>	5.5			V					10mA					
DC	5.5			V						10mA				
OE	5.5			V							10mA			
Output Short Circuit Current (82S63)	-20		-70	mA								0V		9, 11
Power/Current Consumption														9
(8263)		378/72	420/80	mW/mA				0V						
(8264)		400/76	475/90.4	mW/mA				0V						

TYPICAL APPLICATIONS

An approach to expanding the 8264 (bare collector output) is shown in Figure 1. The idea is to use common collectors with external pull-up resistors (one resistor for each of the four outputs) and make use of the output enable code.

As can be seen, the channel select lines are tied common, while a different enable code would be used to select a particular 8264. All non-selected 8264's have their outputs in the logic "1" condition, thus allowing the selected multiplexer to predominate.

Figure 2 illustrates a typical example using the 8263 (totem pole output) along with the 8281 (4-bit binary counter) and the 8270/71 (4-bit shift register), to implement a variable modulus counter. The 8270's act as a 3-register memory. The outputs of the 8270's are fed to the corresponding inputs of the 8263. Now there are three different pre-settable 4-bit words that can be chosen by the 8264. By alternating the channel select codes, the 8281 counter is preset with one of three words and produces an output whose repetition rate is dependent on the inputs from the multiplexer.

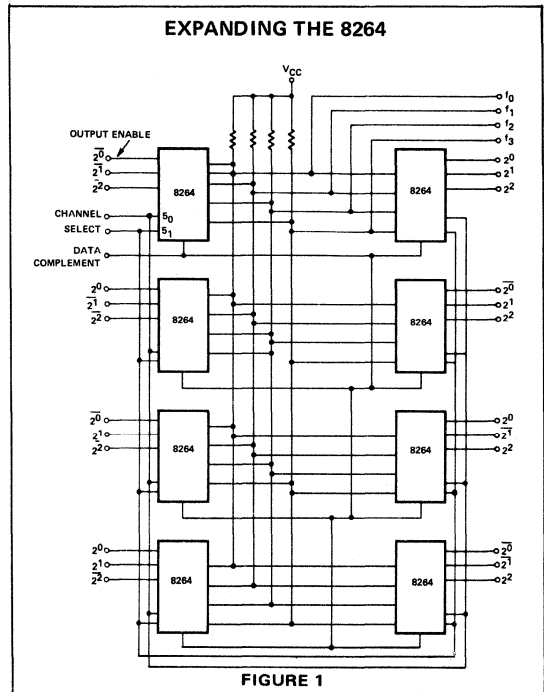


FIGURE 1

VARIABLE MODULUS COUNTER

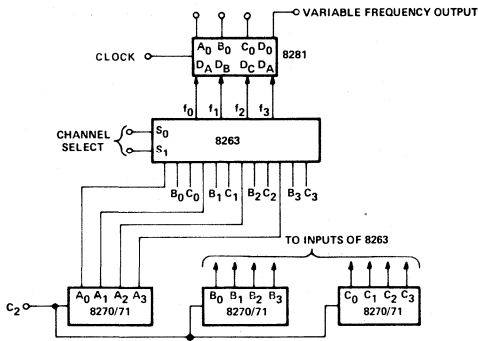
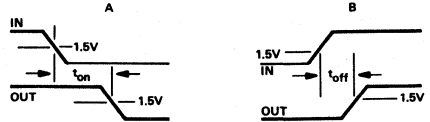
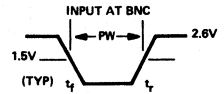


FIGURE 2

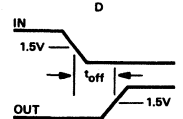
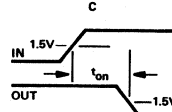
WAVEFORMS

NON-INVERTING PATHS

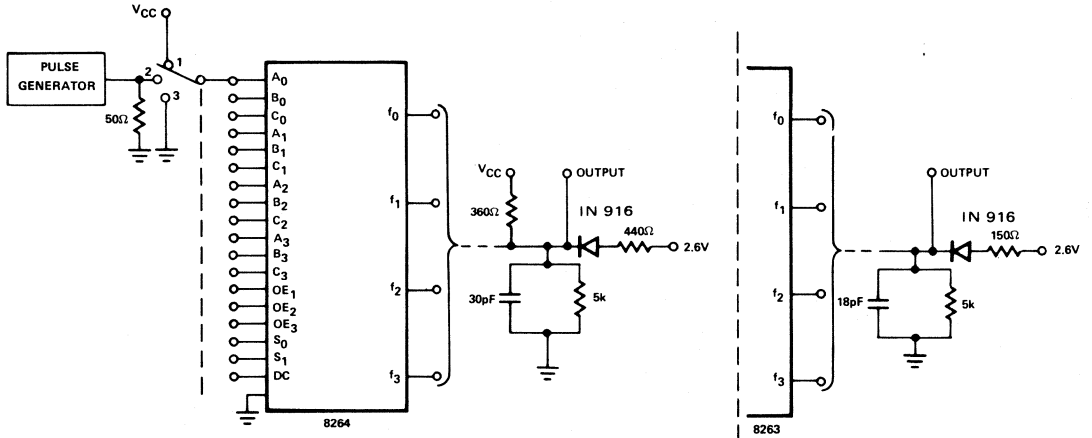
$t_r = t_f < 3ns$   
 Amplitude = 2.6V  
 PW = 200ns  
 PRR = 1MHz



INVERTING PATHS



AC TEST FIGURE



NOTE

1. Scope terminals to be < 1¼" from package pins.

2. Position 1 on switch provides a logical "1". Position 2 on switch provides pulse. Position 3 on switch provides a logical "0".
3. All measurements are made at 1.5V level.
4. See truth table for logical conditions.

AC TESTING

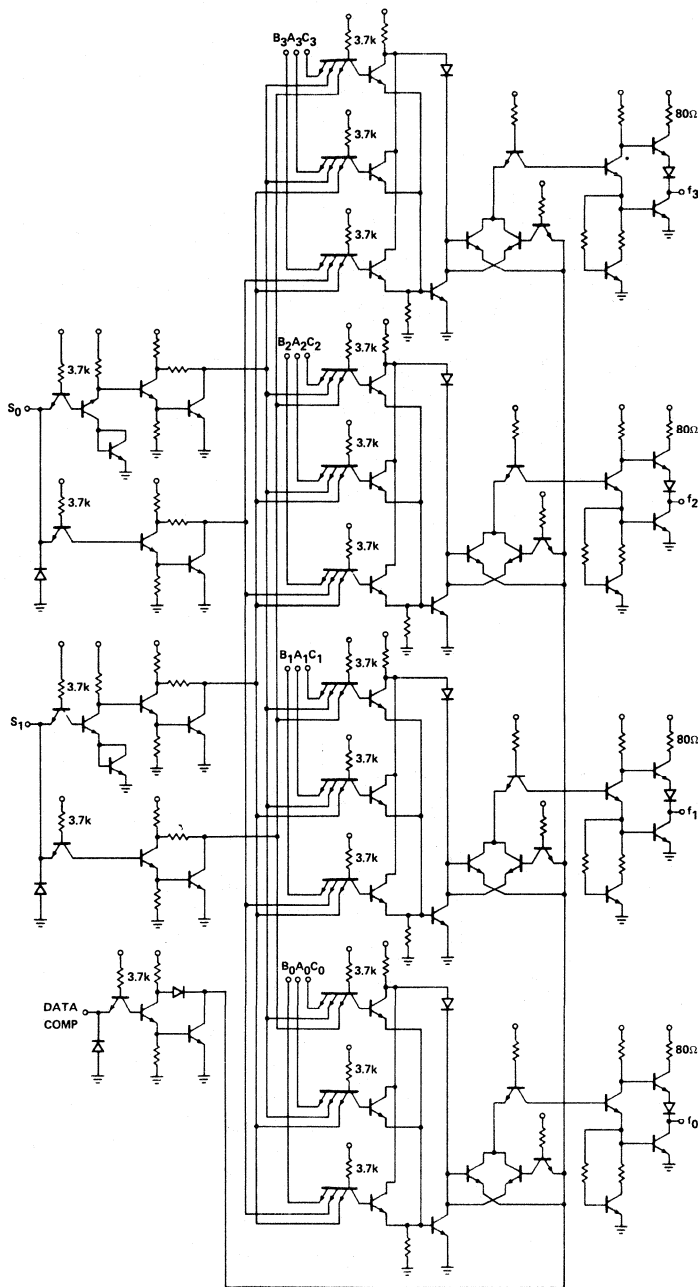
Step No.	Delay From-To	Driven Inputs	Switching Positions															Waveform Types																	
			Other Inputs																																
			A0	B0	C0	A1	B1	C1	A2	B2	C2	A3	B3	C3	OE	OE	OE		S0	S1	DC														
1	A <sub>n</sub> to f <sub>n</sub>	2	2	1	1	2	1	1	2	1	1	2	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	C, D
2	S0 to f <sub>n</sub>	2	3	1	1	3	1	1	3	1	1	3	1	1	1	1	1	1	1	2	1	1	1	1	1	1	1	1	1	1	1	1	1	1	A, B
3	S0 to f <sub>n</sub>	2	1	3	1	1	3	1	1	3	1	1	3	1	1	1	1	1	1	2	1	1	1	1	1	1	1	1	1	1	1	1	1	1	C, D
4	S1 to f <sub>n</sub>	2	1	1	3	1	1	3	1	1	3	1	1	3	1	1	1	1	1	1	2	1	1	1	1	1	1	1	1	1	1	1	1	1	C, D
5	DC to f <sub>n</sub>	2	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	C, D
6	OE <sub>n</sub> to f <sub>n</sub>	2	1	1	1	1	1	1	1	1	1	1	1	1	1	1	*	*	*	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	C, D

NOTE: Step number 6 is for 8264 only.

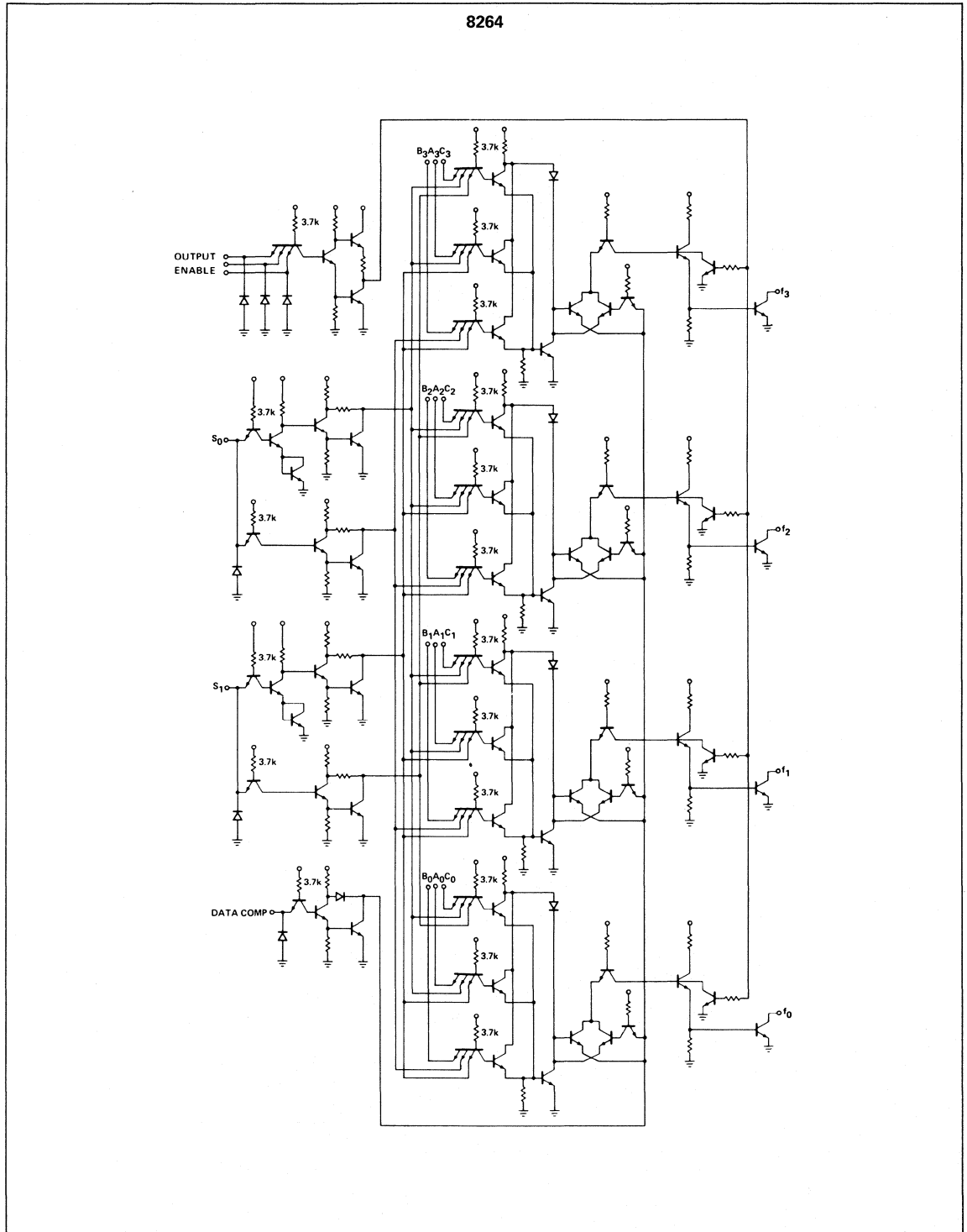
\* Test one input at a time - others remain at "1".

SCHEMATIC DIAGRAMS

8263



SCHEMATIC DIAGRAMS (Cont'd)



### DIGITAL 8000 SERIES TTL/MSI

#### DESCRIPTION

The 8266/8267 2-Input, 4-Bit Digital Multiplexer is a monolithic array utilizing familiar TTL circuit structures. The 8267 features a bare-collector output to allow expansion with other devices.

The multiplexer is intended for use at the inputs to adders, registers and in other parallel data handling applications.

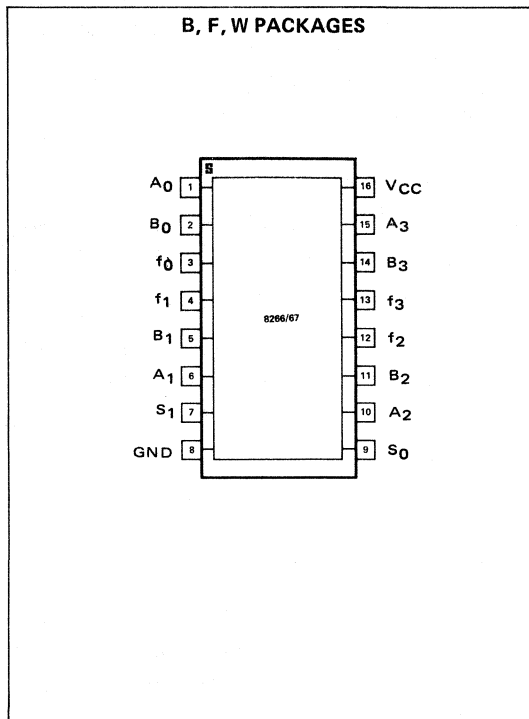
The multiplexer is able to choose from two different input sources, each containing 4 bits:  $A = (A_0, A_1, A_2, A_3)$ ,  $B = (B_0, B_1, B_2, B_3)$ . The selection is controlled by the input  $S_0$ , while the second control input,  $S_1$ , is held at zero.

For conditional complementing, the two inputs ( $A_n, B_n$ ) are tied together to form the function TRUE/COMPLEMENT, which is needed in conjunction with added elements to perform ADDITION/SUBTRACTION. Further, the inhibit state  $S_0 = S_1 = 1$  can be used to facilitate transfer operations in an arithmetic section.

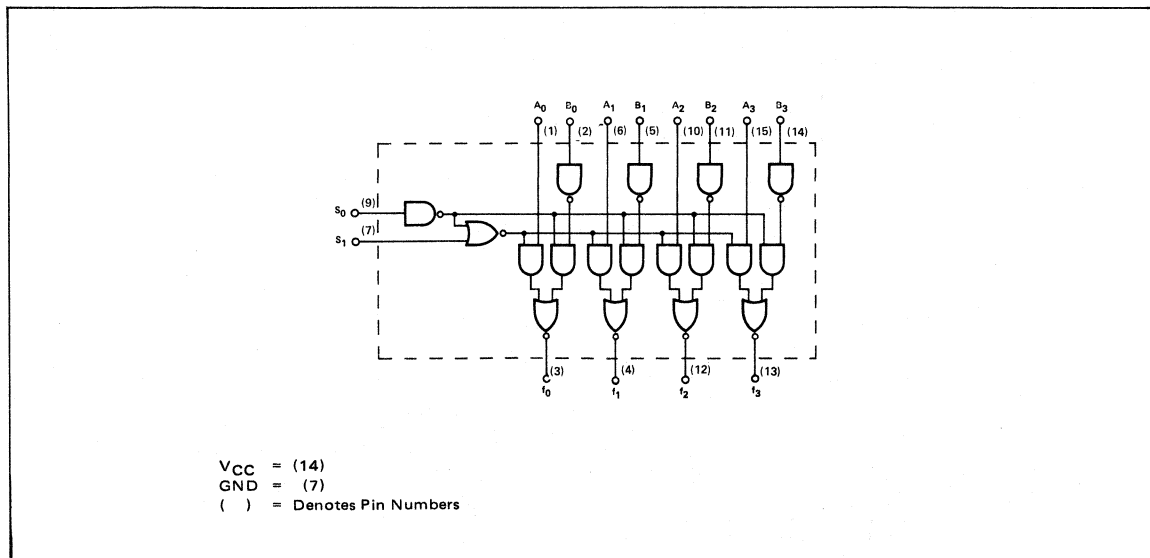
#### TRUTH TABLE

SELECT LINES		OUTPUTS
$S_0$	$S_1$	$f_n (0, 1, 2, 3)$
0	0	$B_n$
0	1	$\overline{B_n}$
1	0	$\overline{A_n}$
1	1	1

#### PIN CONFIGURATIONS (Top View)



#### LOGIC DIAGRAM



# SIGNETICS 2-INPUT, 4-BIT DIGITAL MULTIPLEXER ■ 8266/67

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	A <sub>n</sub>	B <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	OUTPUTS	
"1" Output Voltage (8266)	2.6	3.5		V	0.8V	2.0V	0.8V	0.8V	-800μA	7
"0" Output Voltage			0.40	V	2.0V	2.0V	2.0V	0.8V	16mA	8
"1" Output Leakage Current (8267)			25	μA	0.6V	2.0V	2.0V	0.8V		10
"0" Input Current										
A <sub>n</sub> , B <sub>n</sub>	-0.1		-1.6	mA	0.4V	0.4V	0V	0V		
S <sub>0</sub> , S <sub>1</sub>	-0.1		-1.6	mA			0.4V	0.4V		
"1" Input Current										
A <sub>n</sub> , B <sub>n</sub>			40	μA	4.5V	4.5V		2.0V		
S <sub>0</sub> , S <sub>1</sub>			40	μA			4.5V	4.5V		
Input Voltage Rating										
S <sub>0</sub> , A <sub>n</sub> , B <sub>n</sub>	5.5			V	10mA	10mA	10mA	2.0V		
S <sub>1</sub>	5.5			V			2.0V	10mA		
Output Short Circuit Current (8266)	-20		-70	mA					0V	11, 12

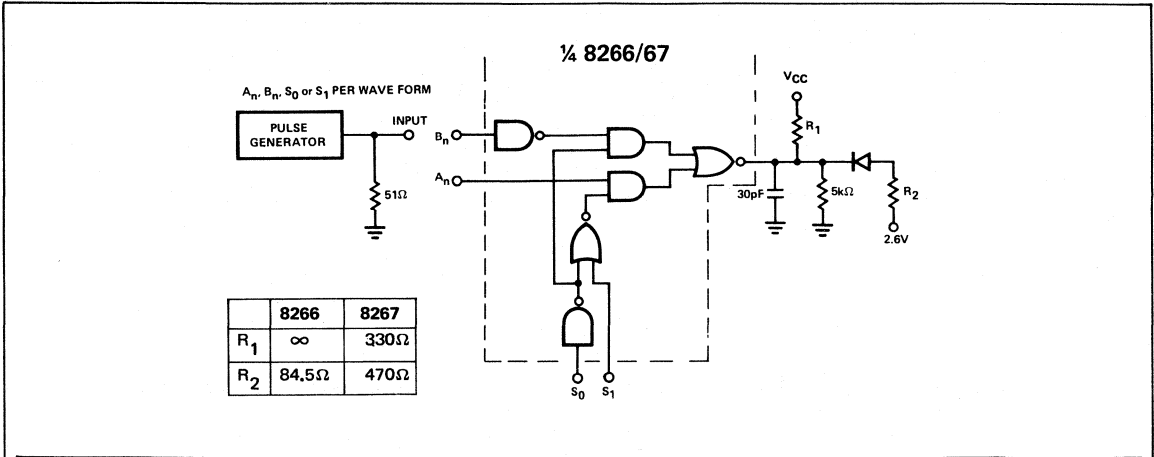
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	A <sub>n</sub>	B <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	OUTPUTS	
Propagation Delay (8266)										
S <sub>0</sub> to f <sub>n</sub> (short path)		18	28	ns						9
S <sub>0</sub> to f <sub>n</sub> (long path)		20	30	ns						9
A <sub>n</sub> to f <sub>n</sub>		13	20	ns						9
B <sub>n</sub> , S <sub>1</sub> to f <sub>n</sub>		14	25	ns						9
Propagation Delay (8267)										
S <sub>0</sub> to f <sub>n</sub>		27	36	ns						9
A <sub>n</sub> to f <sub>n</sub>		15	20	ns						9
B <sub>n</sub> , S <sub>1</sub> to f <sub>n</sub>		21	28	ns						9
S <sub>0</sub> to f <sub>n</sub> (short path)		18	28	ns						9
Power/Current Consumption		200/ 38.1	275/ 52.4	mW/ mA	4.5V	0V	4.5V	0V		12

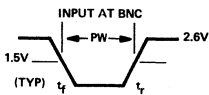
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each gate element independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>. Refer to AC Test Figure.
- Connect an external 1k ± 1% resistor from V<sub>CC</sub> to the output for this test.
- Not more than one output should be shorted at a time.
- V<sub>CC</sub> = 5.25 volts.

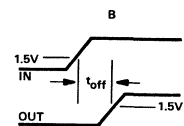
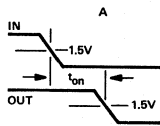
AC TEST FIGURE AND WAVEFORMS



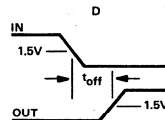
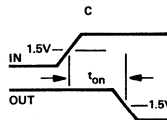
NON-INVERTING PATHS



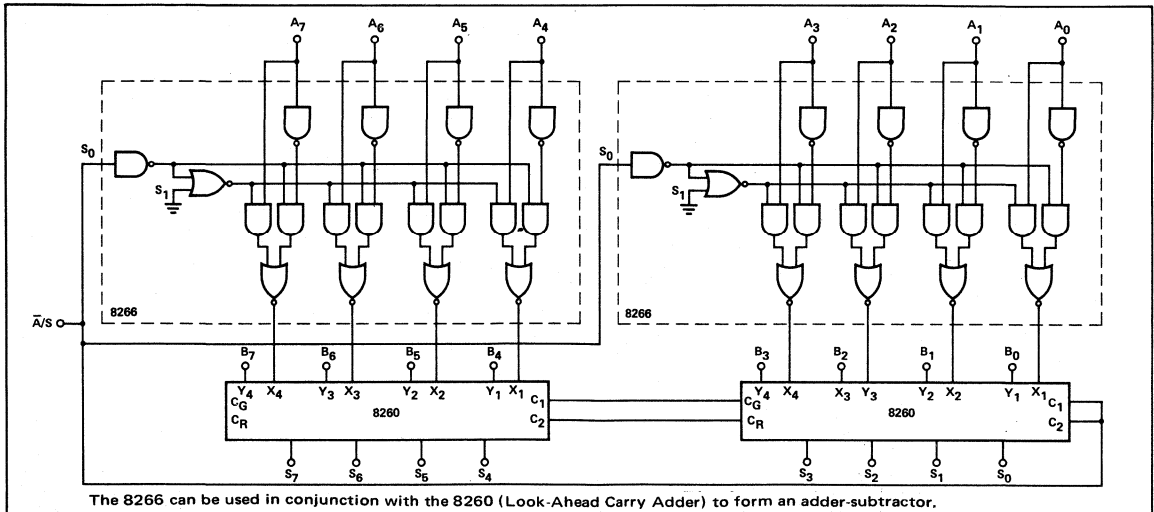
$t_r = t_f \leq 5ns$   
 Amplitude = 2.6V  
 PW = 200ns  
 PRR = 1MHz



INVERTING PATHS

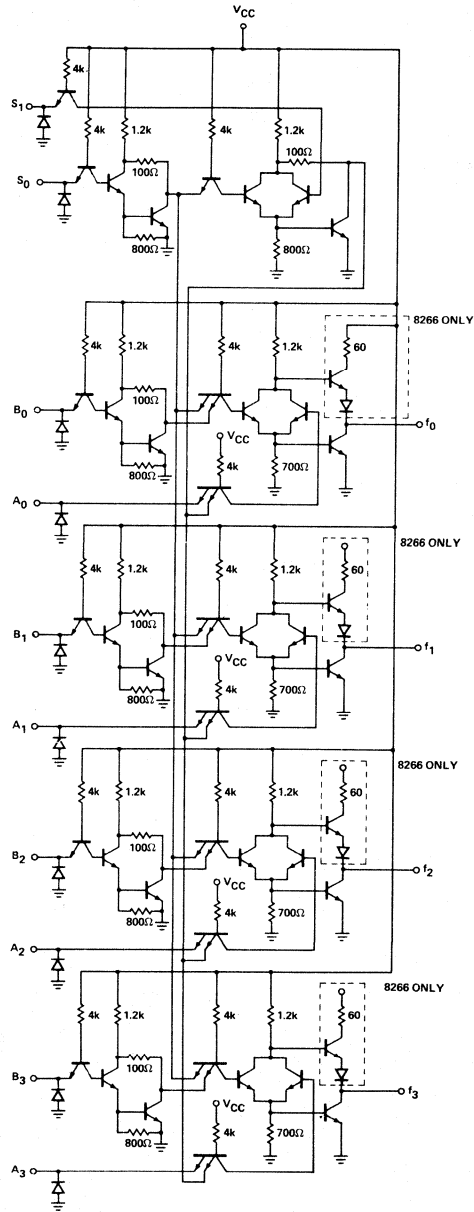


TYPICAL APPLICATIONS



The 8266 can be used in conjunction with the 8260 (Look-Ahead Carry Adder) to form an adder-subtractor.

SCHEMATIC DIAGRAM





## DIGITAL 8000 SERIES TTL/MSI

### DESCRIPTION

The 8268 is a single-bit full adder with gated true and complementary inputs, complementary sum ( $\Sigma$  and  $\bar{\Sigma}$ ) outputs and an inverted carry output. By taking advantage of the unique true or inverted inputs and true or inverted outputs, parallel addition speed is greatly enhanced (by eliminating unnecessary inversions).

The device is designed for medium speed parallel and serial adder systems.

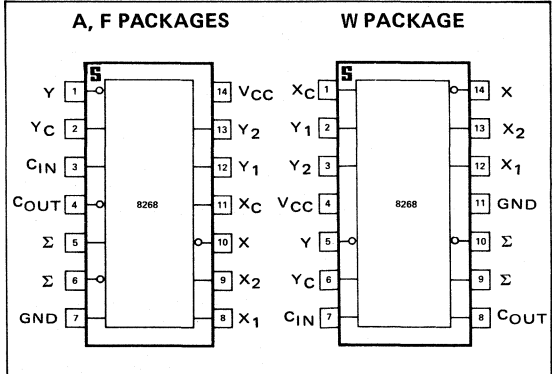
### TRUTH TABLE (See Notes 1, 2 and 3)

C <sub>IN</sub>	Y	X	$\bar{C}_{OUT}$	$\Sigma$	$\bar{\Sigma}$
0	0	0	1	0	1
0	0	1	1	1	0
0	1	0	1	1	0
0	1	1	0	0	1
1	0	0	1	1	0
1	0	1	0	0	1
1	1	0	0	0	1
1	1	1	0	1	0

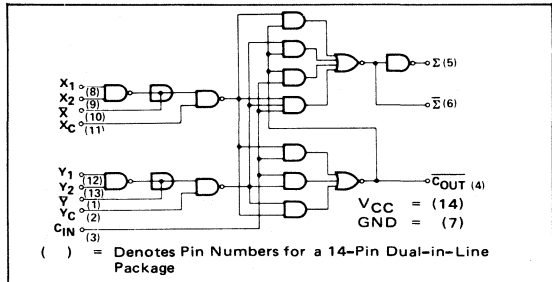
#### NOTES:

- $X = \bar{X} \cdot X_c$ ;  $Y = \bar{Y} \cdot Y_c$   
where  $\bar{X} = X_1 \cdot Y_2$ ;  $\bar{Y} = Y_1 \cdot Y_2$
- When  $\bar{X}$  or  $\bar{Y}$  are used as inputs,  $X_1$  and  $X_2$  or  $Y_1$  and  $Y_2$  respectively must be tied to GND.
- When  $X_1$  and  $X_2$  or  $Y_1$  and  $Y_2$  are used as inputs,  $\bar{X}$  or  $\bar{Y}$  respectively must be left open or used to perform the WIRED-AND function.

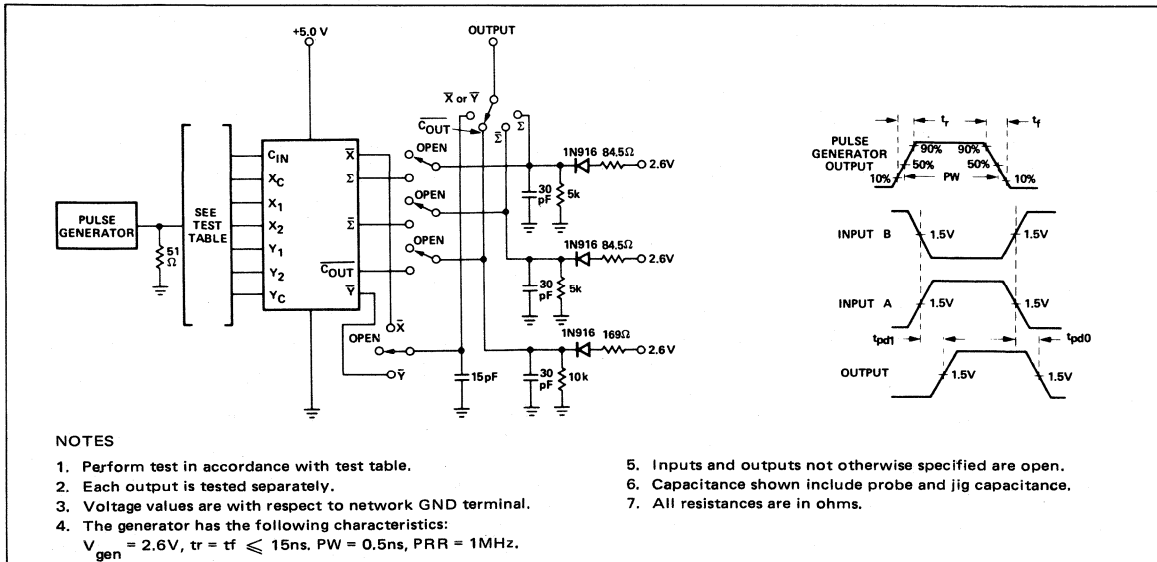
### PIN CONFIGURATIONS (Top View)



### LOGIC DIAGRAM



### AC TEST FIGURE AND WAVE FORMS



#### NOTES

- Perform test in accordance with test table.
- Each output is tested separately.
- Voltage values are with respect to network GND terminal.
- The generator has the following characteristics:  
 $V_{gen} = 2.6V$ ,  $t_r = t_f \leq 15ns$ ,  $PW = 0.5ns$ ,  $PRR = 1MHz$ .
- Inputs and outputs not otherwise specified are open.
- Capacitance shown include probe and jig capacitance.
- All resistances are in ohms.

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS										NOTES
	MIN.	TYP.	MAX.	UNITS	X <sub>1</sub>	X <sub>2</sub>	X	X <sub>c</sub>	Y <sub>1</sub>	Y <sub>2</sub>	Y	Y <sub>c</sub>	C <sub>IN</sub>	OUTPUTS	
"1" Output Voltage	2.6	3.5		V	0.8V	0.8V	2.0V	2.0V	0.8V	0.8V	0.8V	2.0V	0.8V	-500μA	6
"0" Output Voltage			0.4	V	0.8V	0.8V	2.0V	2.0V	0.8V	0.8V	2.0V	2.0V	0.8V	16mA	7
"0" Input Current															
X <sub>1</sub>	-0.1		-1.6	mA	0.4V	4.5V									
X <sub>2</sub>	-0.1		-1.6	mA	4.5V	0.4V									
X <sub>c</sub>	-0.1		-2.6	mA	0.0V	0.0V	0.4V	4.5V							
Y <sub>1</sub>	-0.1		-1.6	mA	0.0V	0.0V		0.4V	0.4V	4.5V					
Y <sub>2</sub>	-0.1		-1.6	mA					4.5V	0.4V					
Y <sub>c</sub>	-0.1		-2.6	mA					0.0V	0.0V	0.4V	4.5V			
C <sub>IN</sub>	-0.1		-1.6	mA					0.0V	0.0V		0.4V			
C <sub>IN</sub>	-0.1		-8.0	mA									0.4V		
"1" Input Current															
X <sub>1</sub>			40	μA	4.5V										
X <sub>2</sub>			40	μA	0.0V										
X <sub>c</sub>			40	μA			0.0V	4.5V							
Y <sub>1</sub>			40	μA					4.5V	4.5V					
Y <sub>2</sub>			40	μA					0.0V	0.4V					
Y <sub>c</sub>			40	μA							0.0V	4.5V			
C <sub>IN</sub>			160	μA	0.0V	0.0V			0.0V	0.0V			4.5V		
Input Voltage Rating															
X <sub>1</sub>	5.5			V	10mA	0.0V									12
X <sub>2</sub>	5.5			V	0.0V	10mA									
X <sub>c</sub>	5.5			V			0.0V	10mA							
Y <sub>1</sub>	5.5			V					10mA	0.0V					
Y <sub>2</sub>	5.5			V					0.0V	10mA					
Y <sub>c</sub>	5.5			V							0.0V	10mA			
C <sub>IN</sub>	5.5			V									10mA		

T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

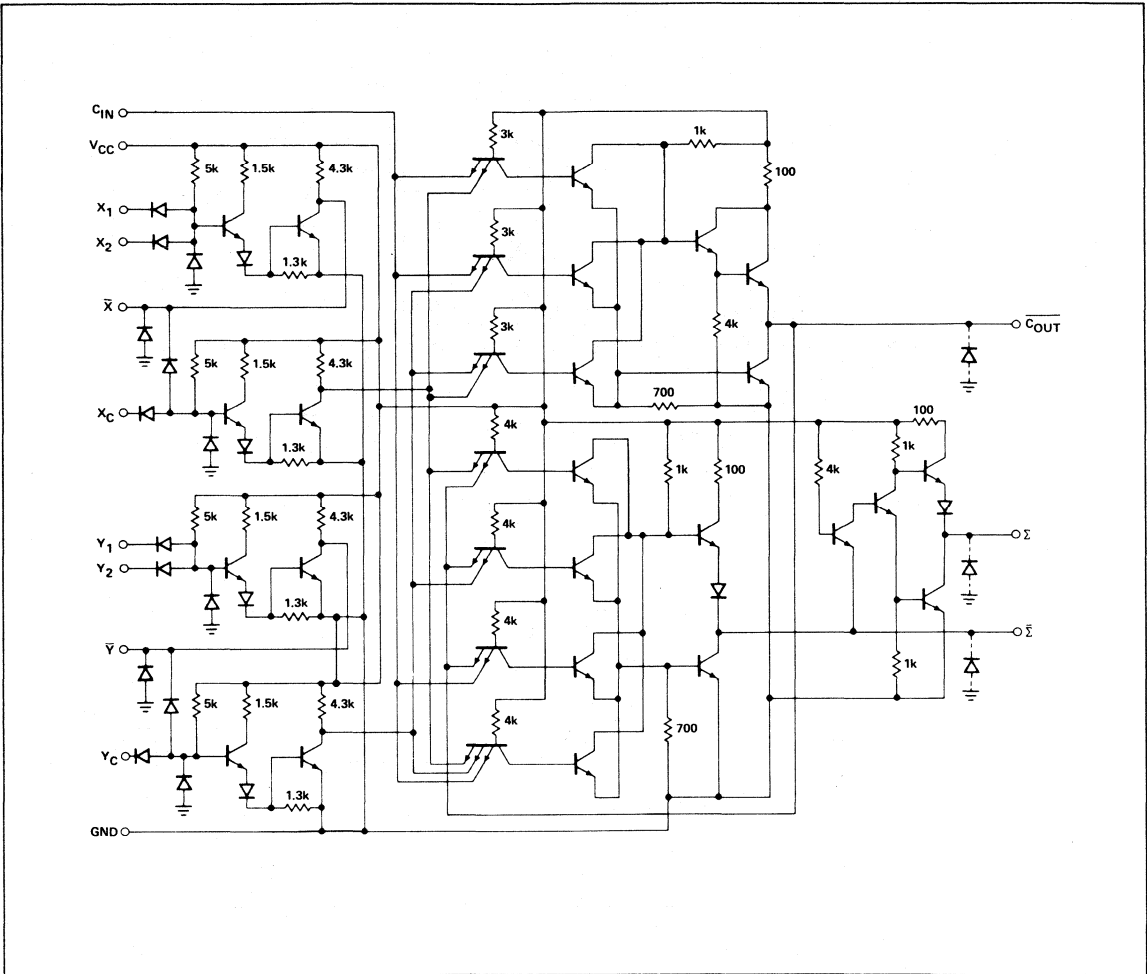
CHARACTERISTICS	LIMITS				TEST CONDITIONS										NOTES
	MIN.	TYP.	MAX.	UNITS	X <sub>1</sub>	X <sub>2</sub>	X	X <sub>c</sub>	Y <sub>1</sub>	Y <sub>2</sub>	Y	Y <sub>c</sub>	C <sub>IN</sub>	OUTPUTS	
Power/Current Consumption		152/29	185/35	mW/mA											11
Output Short															
Circuit Current (Σ)	-18		-57	mA	0.0V	0.0V			0.0V	0.0V	0.0V		2.0V	0.0V	10, 11
Output Short															
Circuit Current (Σ̄)	-18		-57	mA	0.0V	0.0V			0.0V	0.0V			0.0V	0.0V	10, 11
Output Short															
Circuit Current (C̄ <sub>out</sub> )	-18		-70	mA	0.0V	0.0V			0.0V	0.0V			0.0V	0.0V	10, 11
t <sub>pd</sub> 1 C <sub>in</sub> to C̄ <sub>out</sub>		8	13	ns											8
t <sub>pd</sub> 0 C <sub>in</sub> to C̄ <sub>out</sub>		8	13	ns											8
t <sub>pd</sub> 1 Y <sub>c</sub> to C̄ <sub>out</sub>		20	25	ns											8
t <sub>pd</sub> 0 Y <sub>c</sub> to C̄ <sub>out</sub>		20	25	ns											8
t <sub>pd</sub> 1 X <sub>c</sub> to Σ		35	45	ns											8
t <sub>pd</sub> 0 X <sub>c</sub> to Σ		35	45	ns											8
t <sub>pd</sub> 1 Y <sub>c</sub> to Σ̄		25	35	ns											8
t <sub>pd</sub> 0 Y <sub>c</sub> to Σ̄		25	35	ns											8
t <sub>pd</sub> X <sub>1</sub> , X <sub>2</sub> to X̄		30	40	ns											8, 9
t <sub>pd</sub> 0 X <sub>1</sub> , X <sub>2</sub> to X̄		15	20	ns											8, 9
t <sub>pd</sub> 1 Y <sub>1</sub> , Y <sub>2</sub> to Ȳ		30	40	ns											8, 9
t <sub>pd</sub> 0 Y <sub>1</sub> , Y <sub>2</sub> to Ȳ		15	20	ns											8, 9

**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.

- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figure.
- This test is a measure of the required worst-case data set-up time.
- Not more than one output should be shorted at a time.
- V<sub>CC</sub> = 5.25 volts.
- The total time required to perform the ADD function may be determined by summing the delays from X<sub>1</sub>, X<sub>2</sub> to X̄ or Y<sub>1</sub>, Y<sub>2</sub> to Ȳ with the delay from X<sub>c</sub> or Y<sub>c</sub> to Σ or Σ̄.

**SCHEMATIC DIAGRAM**

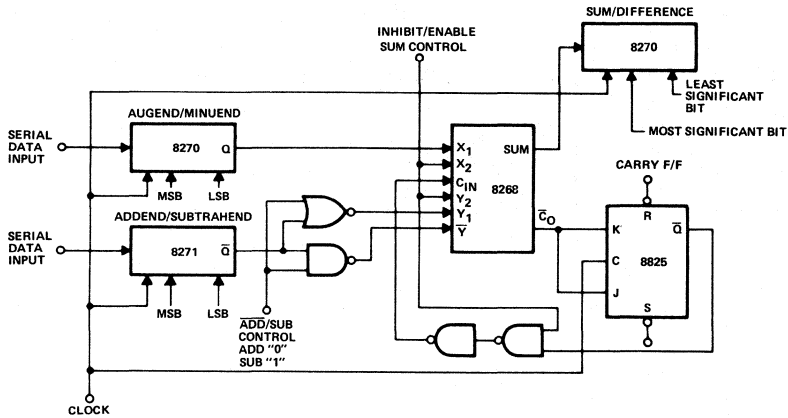


**TEST TABLE** (See Note 5)

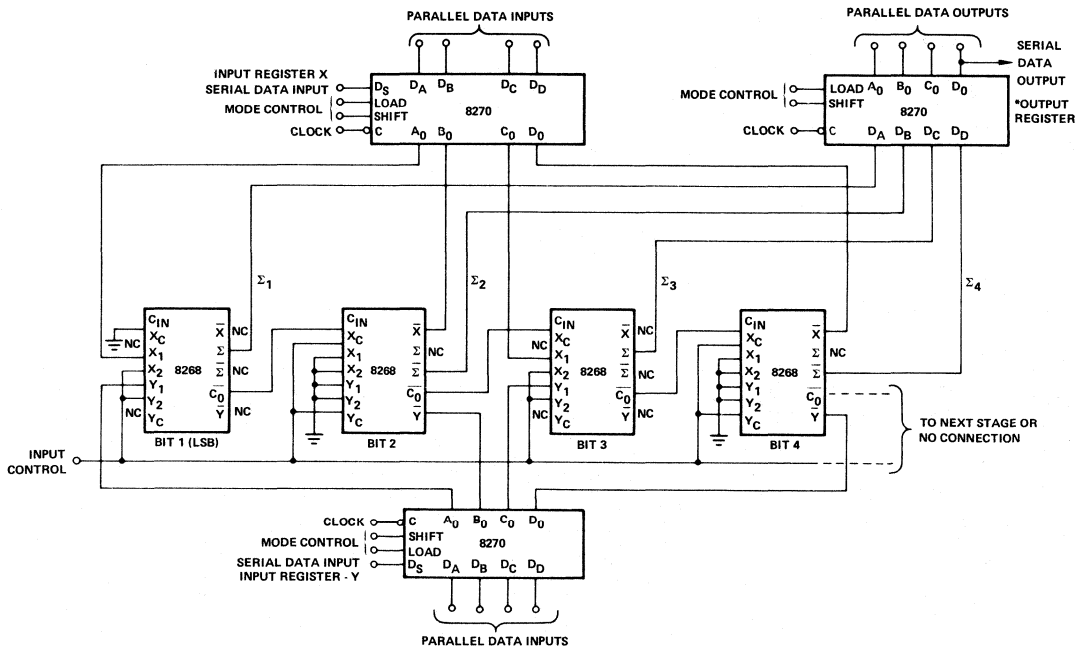
TEST NO.	OUTPUTS UNDER TEST	APPLY INPUT A TO	APPLY INPUT B TO	APPLY +2.6V TO	APPLY GND TO	APPLY OUTPUT LOADING TO
1	$\bar{C}_{out}$	None	$C_{in}$	None	$Y_1$	$\bar{C}_{out}$
2	$C_{out}$	None	$C_{in}$	None	$Y_1$	$C_{out}$
3	$\bar{C}_{out}$	$Y_C$	None	$C_{in}$	$X_1, Y_1$	$\bar{C}_{out}$
4	$C_{out}$	$Y_C$	None	$C_{in}$	$X_1, Y_1$	$C_{out}$
5	$\Sigma$	$X_C$	None	$C_{in}$	$X_1, Y_1$	$\Sigma$ $\bar{\Sigma}$ $\bar{C}_{out}$ $\Sigma$ $\bar{\Sigma}$
6	$\Sigma$	$X_C$	None	$C_{in}$	$X_1, Y_1$	$\bar{C}_{out}$ $\Sigma$ $\bar{\Sigma}$ $\bar{C}_{out}$ $\Sigma$
7	$\bar{\Sigma}$	$Y_C$	None	$C_{in}$	$Y_1$	$\bar{\Sigma}$
8	$\bar{\Sigma}$	$Y_C$	None	$C_{in}$	$Y_1$	$\bar{\Sigma}$
9	$\bar{X}$	None	$X_1$	$X_2$	None	$\bar{X}$ (CL = 15 pF)
10	$\bar{X}$	None	$X_1$	$X_2$	None	$\bar{X}$ (CL = 15 pF)
11	$\bar{Y}$	None	$Y_1$	$Y_2$	None	$\bar{Y}$ (CL = 15 pF)
12	$\bar{Y}$	None	$Y_1$	$Y_2$	None	$\bar{Y}$ (CL = 15 pF)

TYPICAL APPLICATIONS

4-BIT SERIAL ADD/SUBTRACTOR



N-BIT PARALLEL ADDER



NOTES

To expand storage register for serial/parallel operation, connect D0 to Ds of next stage and common the mode control lines and the clock line of the first stage to their respective second stage equivalents.

\*NOTE

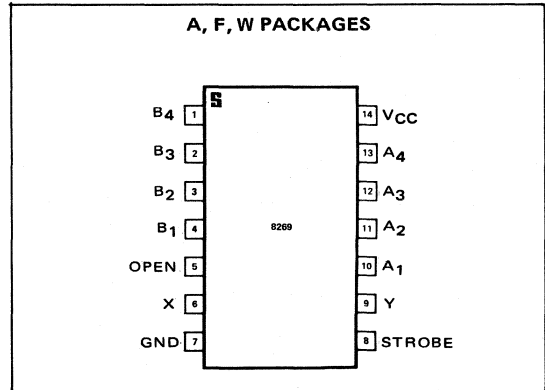
To expand output register for parallel outputs common clock, shift and load lines with their respective counterparts. For serial data output, also connect D0 of first register to Ds of next register.

DIGITAL 8000 SERIES TTL/MSI

## DESCRIPTION

The 8269, a 4 BIT COMPARATOR, is an array of gates designed to perform the numerical comparison of two four-bit binary numbers. The outputs indicate whether the two numbers are equal in value, or which number is the greater. The 8269 is a functional and pin-for-pin replacement for the DM8200.

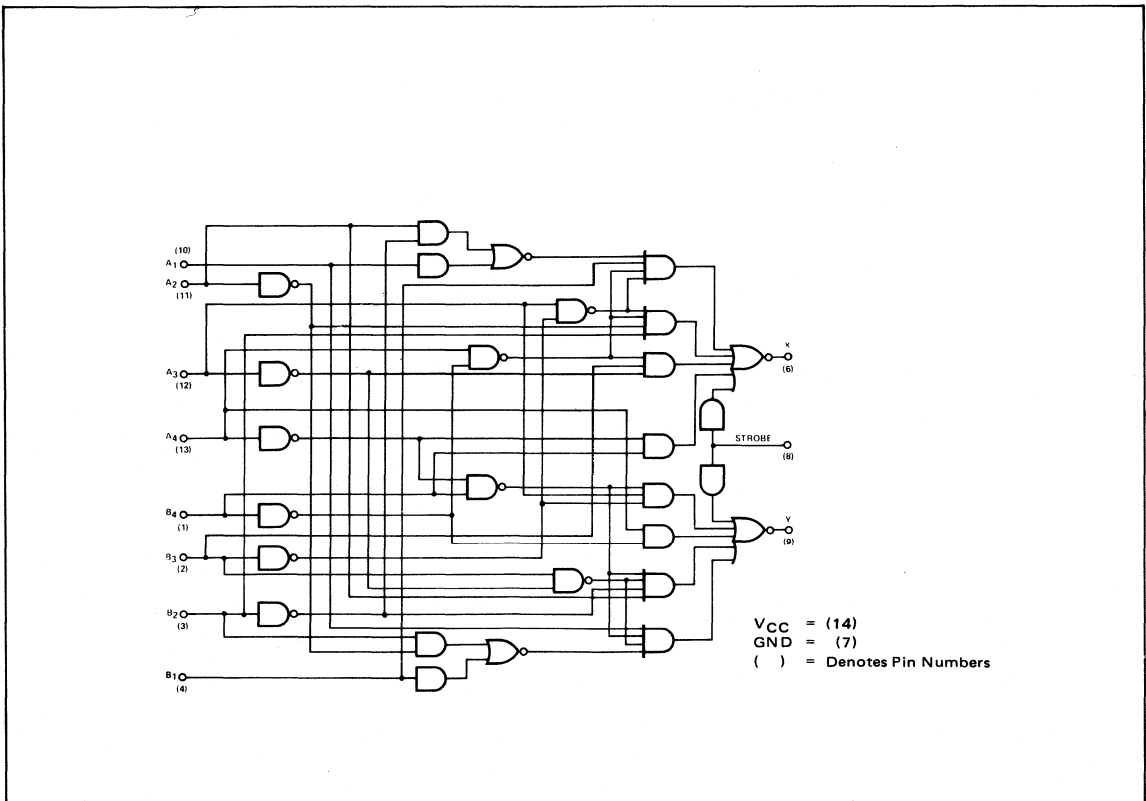
## PIN CONFIGURATIONS (Top View)



## TRUTH TABLE

INPUT			OUTPUT	
A <sub>n</sub>	B <sub>n</sub>	STROBE	X	Y
A	>	B	0	1
A	<	B	0	1
A	=	B	1	1
A	≠	B	1	0

## LOGIC DIAGRAM



ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"1" Output Voltage	2.6	3.5		V	$I_{out} = 800\mu A$ $I_{out} = 16mA$ $V_{in} = 4.5V$ $V_{in} = 0.4V$	6
"0" Output Voltage		0.2	0.4	V		7
"1" Input Current			80	$\mu A$	$V_{CC} = 5.25V$ $V_{out} = 0V, V_{CC} = 5.25V$ $I_{in} = 10mA$	8
"0" Input Current	-0.1		-3.2	mA		
Power Consumption			278/53	mW/mA		
Short Circuit Output Current	-18		-55	mA		
Input Voltage Rating	5.5			V		

$T_A = 25^\circ C$  and  $V_{CC} = 5.0V$

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
Propagation Delay					
tpd1 (Data Input to Output)			40	ns	Test Figure 1
tpd0 (Data Input to Output)			30	ns	Test Figure 1
tpd1 (Strobe to Output)			27	ns	Test Figure 2
tpd0 (Strobe to Output)			18	ns	Test Figure 2

NOTES

- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Not more than one output should be shorted at a time.

AC TEST FIGURE AND WAVEFORMS

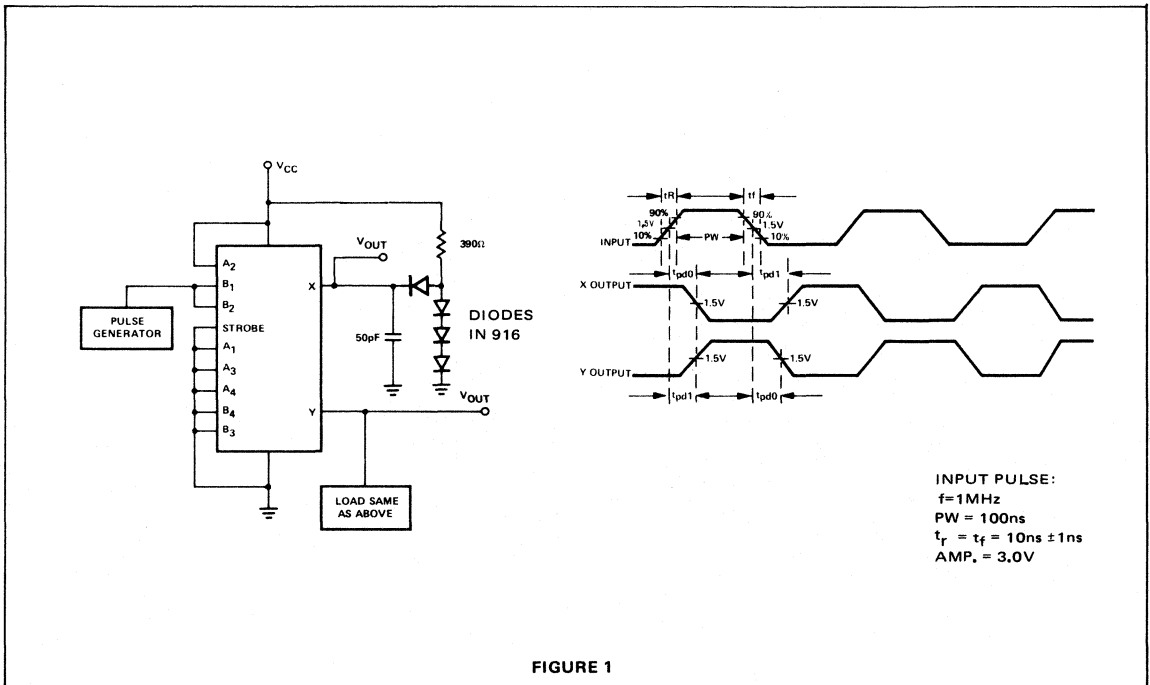


FIGURE 1

AC TEST FIGURES AND WAVEFORMS (Cont'd)

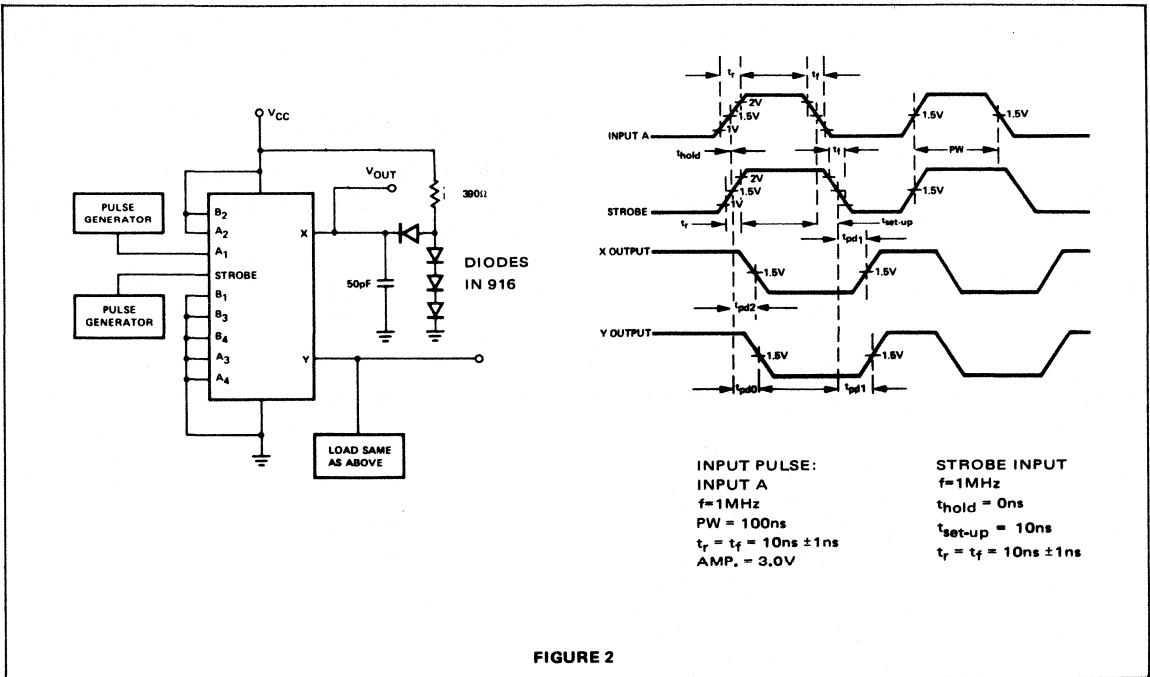


FIGURE 2

### DIGITAL 8000 SERIES TTL/MSI

#### PIN CONFIGURATIONS (Top View)

#### DESCRIPTION

The 8270 is a 4-bit Shift Register with both serial and parallel data entry capability.

The data input lines are single-ended true input data lines which condition their specific register bit location after an enabled clocking transition. Since data transfer is synchronous with clock, data may be transferred in any serial/parallel input/output relationship.

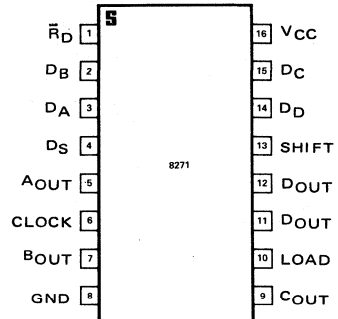
The internal design uses level sensitive binaries which respond to the negative-going clock transition. A buffer clock driver has been included to minimize input clock loading.

Mode control logic is available to determine three possible control states. These register states are serial shift right mode, parallel enter mode, and no change or hold mode. These states accomplish logical decoding for system control. The truth table for the control modes is shown below.

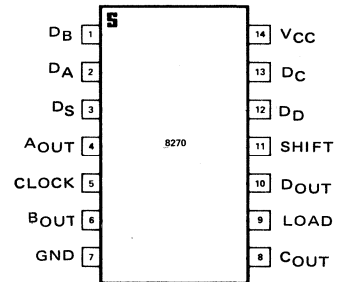
For applications not requiring the hold mode, the load input may be tied high and the shift input used as the mode control.

The 8271 provides a direct reset ( $\overline{RD}$ ), and a  $\overline{D_{out}}$  line in addition to the available outputs of the 8270 element. The fan-out specification for this output is the same as the true outputs of the 8270 element.

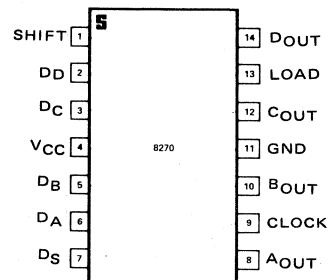
#### B, F, W PACKAGES



#### A, F PACKAGES



#### W PACKAGE



#### TRUTH TABLE

CONTROL STATE	LOAD	SHIFT
Hold	0	0
Parallel Entry	1	0
Shift Right	0	1
Shift Right	1	1



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	LOAD	SHIFT	DATA INPUT	CLOCK	RESET 8271	OUTPUTS	
"1" Output Voltage	2.6	3.5		V	2.0V	0.8V	2.0V	Pulse	2.0V	-800µA	6
"0" Output Voltage			0.4	V	2.0V	0.8V	0.8V	Pulse	2.0V	11.2mA	7
"0" Input Current											
Load	-0.1		-1.2	mA	0.4V						
Shift	-0.1		-1.2	mA		0.4V	0.4V				
Data Input	-0.1		-1.2	mA			0.4V				
Clock	-0.1		-1.2	mA				0.4V			
Reset (8271 only)	-0.1		-1.2	mA					0V		
"1" Input Current											
Load			40	µA	4.5V						
Shift			40	µA		4.5V					
Data Input			40	µA			4.5V				
Clock			40	µA				4.5V			
Reset (8271 only)			40	µA					4.5V		
Input Voltage Rating (All Inputs)	5.5			V	10mA	10mA	10mA	10mA	10mA		

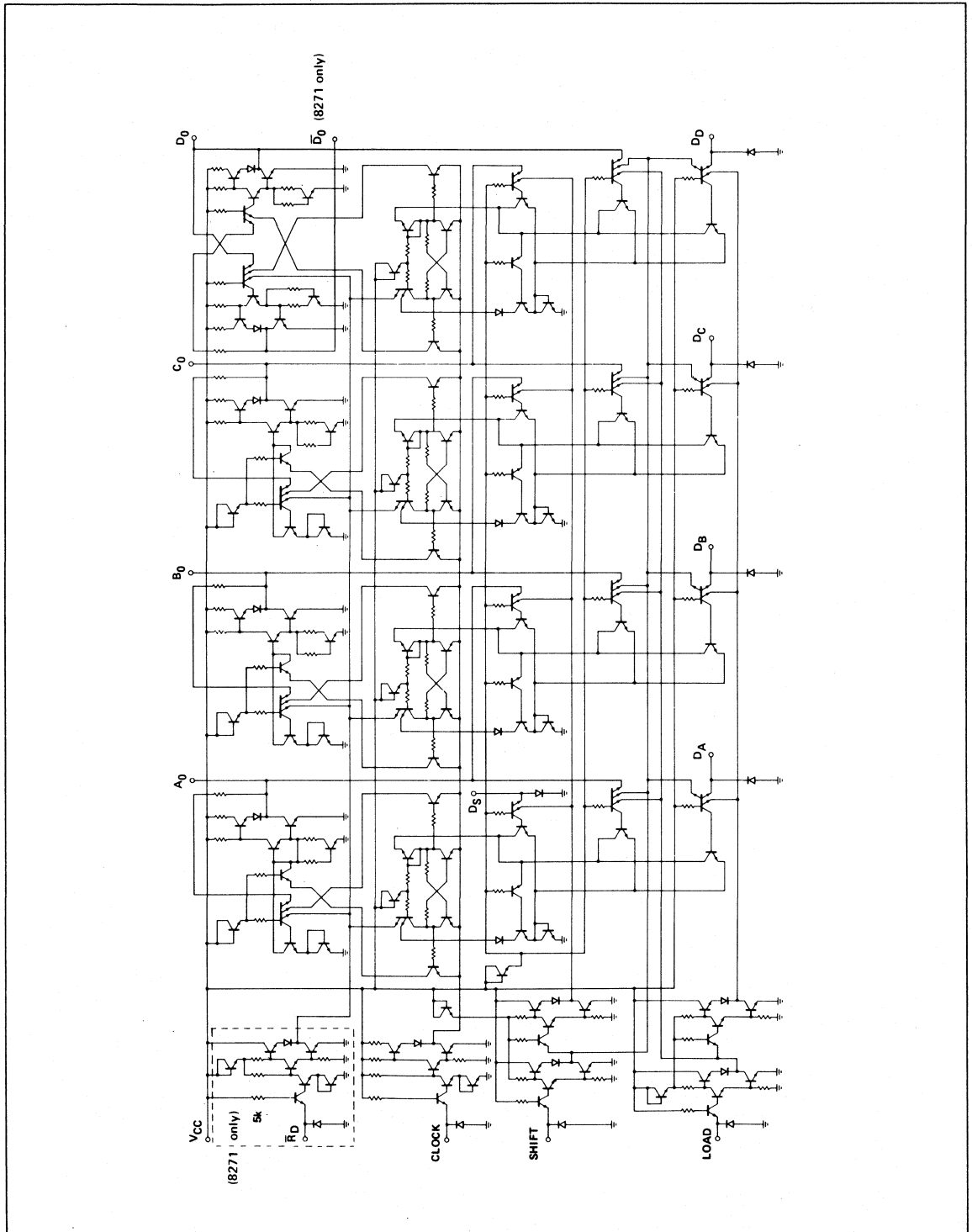
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	LOAD	SHIFT	DATA INPUT	CLOCK	RESET 8271	OUTPUTS	
Power/Current Consumption											
8270 Only		168/32	247/47	mW/mA							9
8271 Only		271/52	344/65	mW/mA							9
Turn-On Delay t <sub>ON</sub>											
All Binaries		25	40	ns							8
Turn-Off Delay t <sub>OFF</sub>											
All Binaries		25	40	ns							8
Clock "1" Interval	20			ns				2.0V			
Transfer Rate	15	22		MHz							
Shift Load Set-Up Time		20	30	ns							
Data Set-Up Time		7	15	ns							

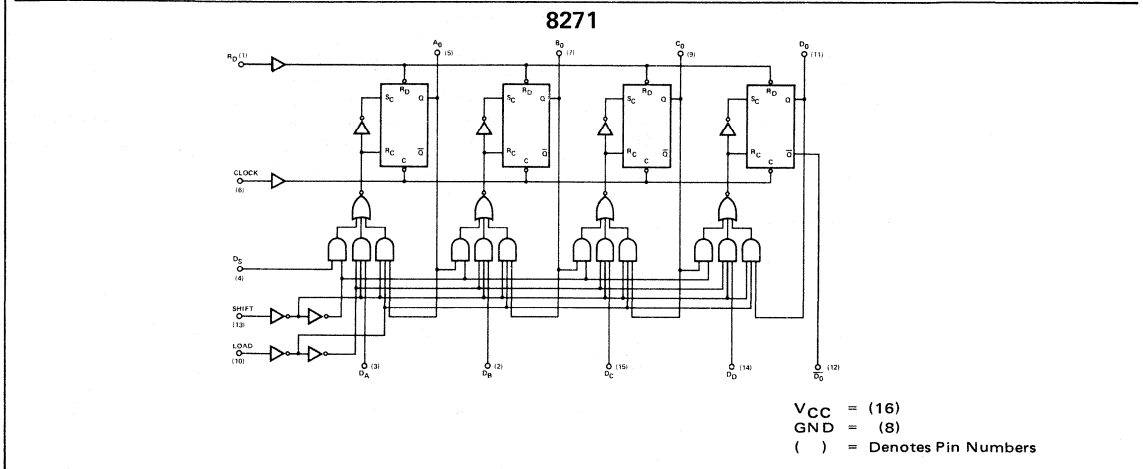
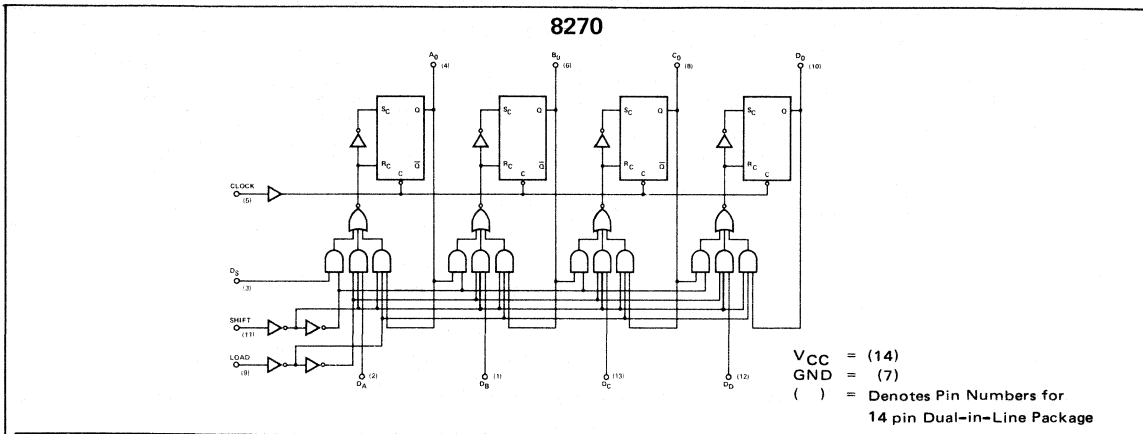
NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Rating should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>. Refer to AC Test Figure.
- V<sub>CC</sub> = 5.25 volts.

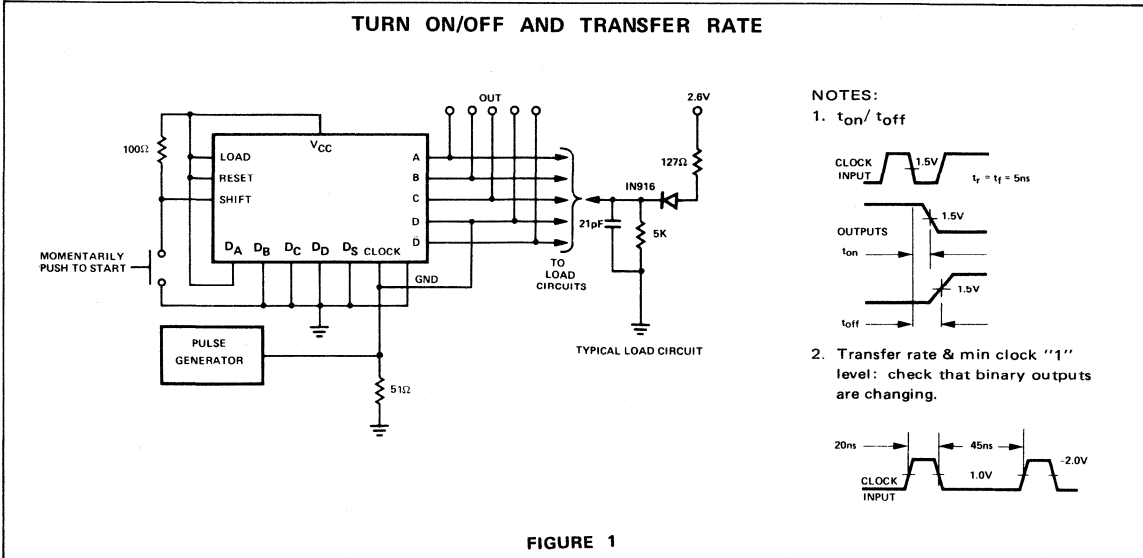
SCHEMATIC DIAGRAM



LOGIC DIAGRAM



AC TEST FIGURES AND WAVEFORMS



AC TEST FIGURES AND WAVEFORMS (Cont'd)

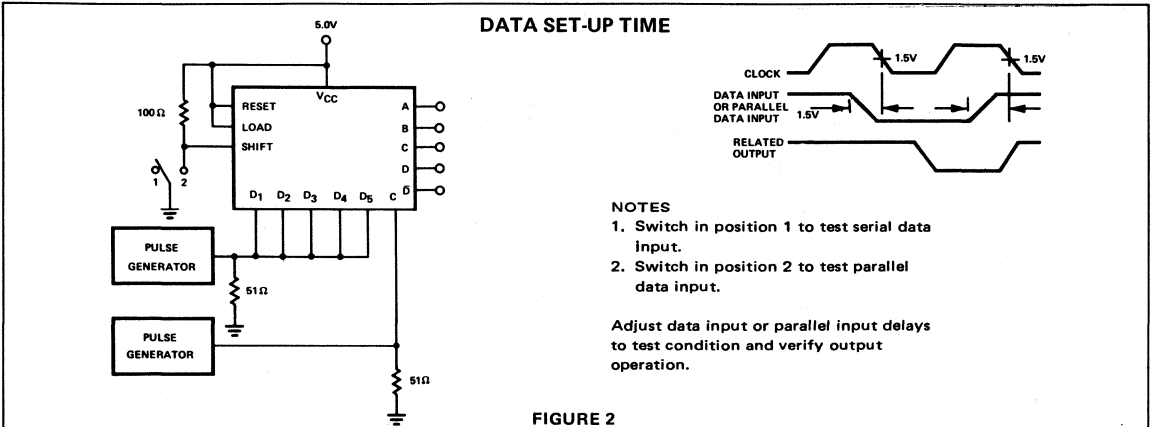


FIGURE 2

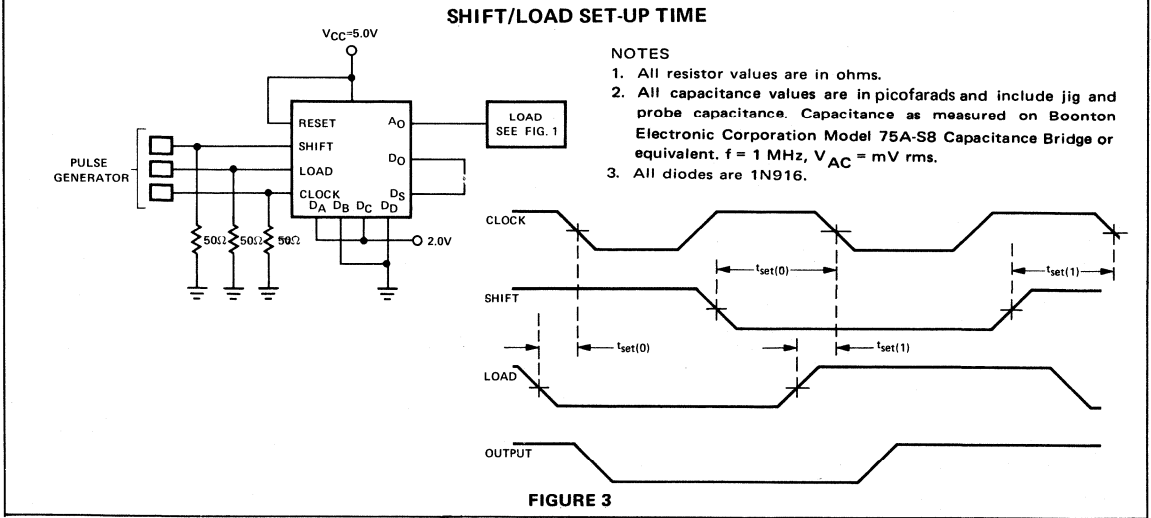
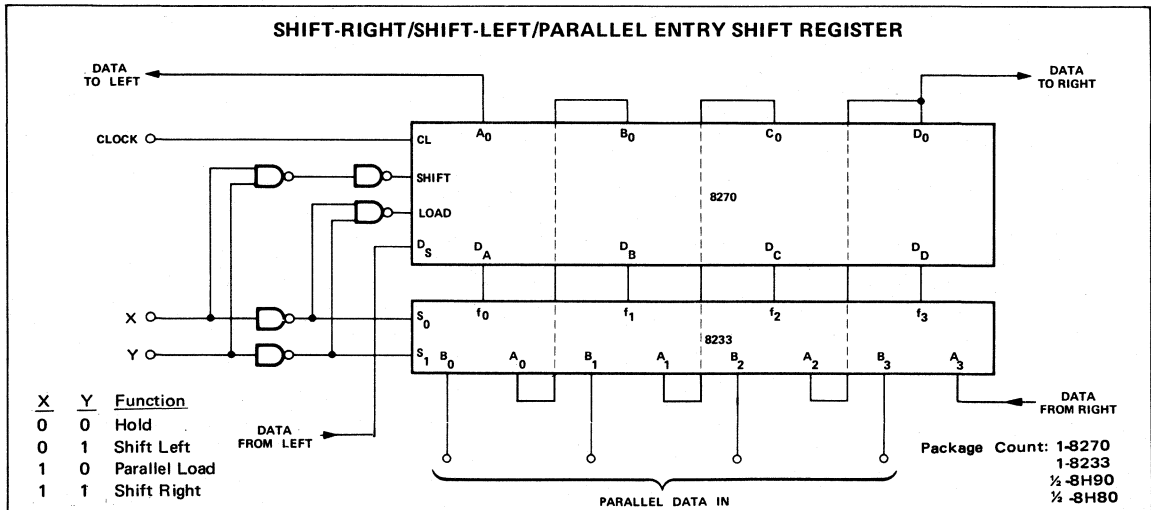


FIGURE 3

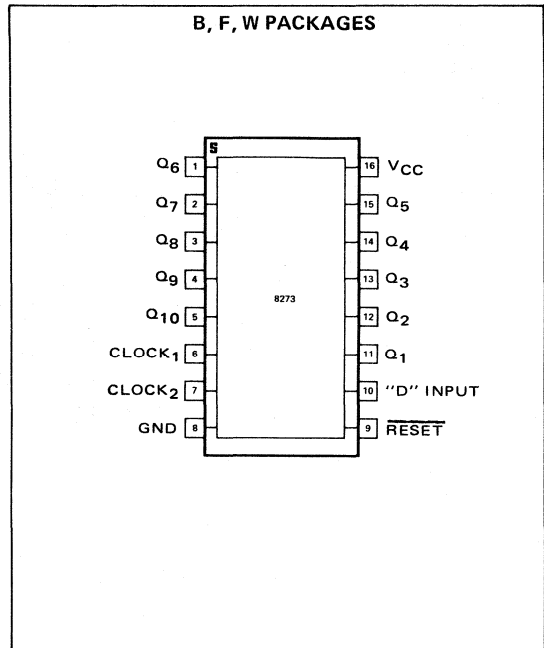
TYPICAL APPLICATIONS



#### DESCRIPTION

The 8273, 10-Bit Shift Register is an array of binary elements interconnected to perform the serial-in, parallel-out shift function. This device utilizes a common buffered reset and operates from either a positive or negative edge clock pulse. Clock 1 is triggered by a negative going clock pulse and Clock 2 is triggered by a positive going clock pulse. The unused clock input performs the inhibit function. The circuit configuration is arranged as a single serial input register with ten true parallel outputs.

#### PIN CONFIGURATIONS (Top View)



#### TRUTH TABLE

INPUT	RESET	CLOCK 1	CLOCK 2	$Q_{n+1}$
1	1	Pulse	0	1
0	1	Pulse	0	0
1	1	1	Pulse	1
0	1	1	Pulse	0
1	1	Pulse	1	Q
0	1	Pulse	1	Q
1	1	0	Pulse	Q
0	1	0	Pulse	Q

NOTE: The unused clock input performs the INHIBIT function.  
**RESET** = 0  $\Rightarrow$  Q = 0

#### ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS	"D" INPUT	CLOCK 1	CLOCK 2	RESET		
"1" Output Voltage	2.6	3.4		V	2.0V	Pulse	0.8V		-500 $\mu$ A	6
"0" Output Voltage		0.2	0.4	V	0.8V	Pulse	0.8V		9.6mA	7
"0" Input Current										
"D" Input	-0.1		-1.6	mA	0.4V					
Clock 1	-0.1		-1.6	mA		0.4V				
Clock 2	-0.1		-1.6	mA			0.4V			
Reset	-0.1		-1.6	mA				0.4V		
"1" Input Current										
"D" Input			40	$\mu$ A	4.5V					
Clock 1			40	$\mu$ A		4.5V				
Clock 2			40	$\mu$ A			4.5V			
Reset			40	$\mu$ A				4.5V		
Input Voltage Rating (All Inputs)	5.5			V	10mA	10mA	10mA	10mA		

SIGNETICS 10-BIT SERIAL-IN, PARALLEL-OUT SHIFT REGISTER ■ 8273

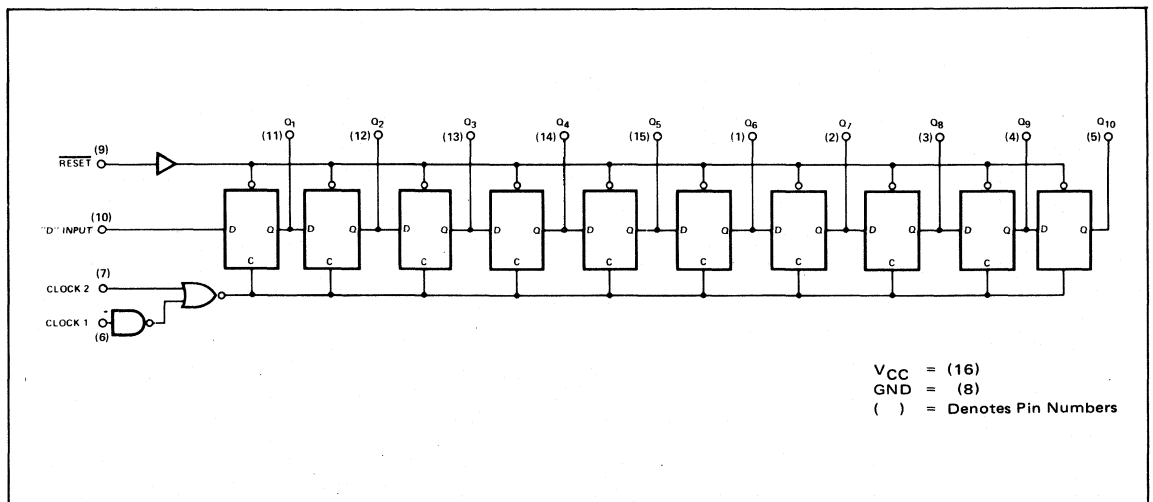
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS	"D" INPUT	CLOCK 1	CLOCK 2	RESET		
Max. Data Transfer Rate	25	35		MHz						
Turn-On Delay t <sub>on</sub>										
Clock 1 to Output		32	40	ns			0.0V	4.5V		10
Clock 2 to Output		28	40	ns				4.5V		10
Reset to Output		35	50	ns		4.5V				10
Turn-Off Delay t <sub>off</sub>										
Clock 1 to Output		25	40	ns			0.0V			10
Clock 2 to Output		19	40	ns		4.5V				10
Clock Pulse Width										
Clock 1		16	25	ns			0.0V			10
Clock 2		12	20	ns		4.5V				10
Set-Up Time (t <sub>set-up</sub> )										
Clock 1			15	ns			0.0V			10
Clock 2			10	ns		4.5V				10
Hold Time (t <sub>hold</sub> )										
Clock 1			15	ns			0.0V			10
Clock 2			10	ns		4.5V				10
Power Consumption/Supply Current		341/65		mW						8
Short Circuit Output Current	-20		103	mA						8,9
Input Voltage Rating (All Inputs)	5.5			V	10mA	10mA	10mA	10mA		

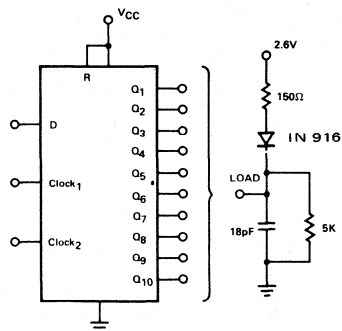
NOTES

- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- V<sub>CC</sub> = 5.25V.
- Not more than one output should be shorted at one time.
- See AC Test Figure.

LOGIC DIAGRAM



AC TEST FIGURE AND WAVEFORMS



NOTES:

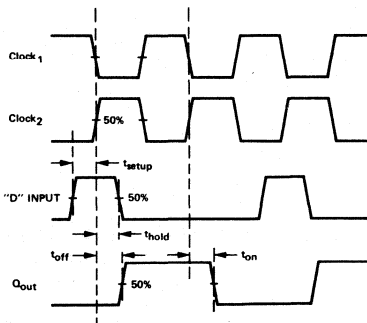
1. Unused clock 2 input must be grounded.

2. Input pulse characteristics

CLOCK

Amplitude = 3.0V

$t_r = t_f \leq 5\text{ns}$ .



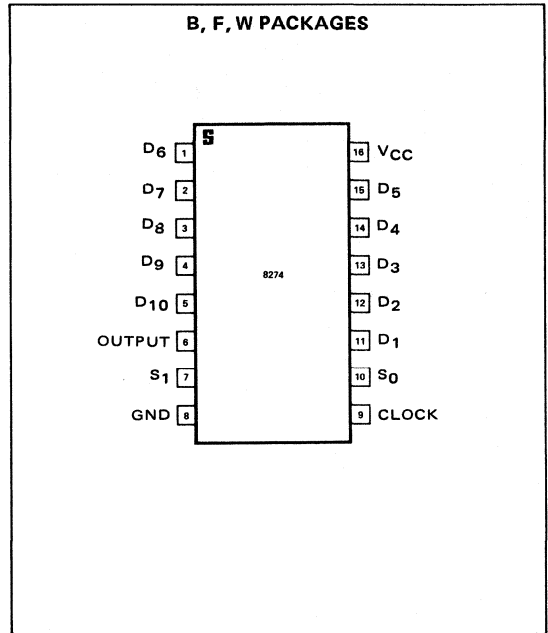
### DESCRIPTION

The 8274 10-Bit Shift Register is an array of binary elements interconnected to perform the parallel-in, serial-out shift function. The circuit has ten parallel inputs and a single true serial output. The D<sub>1</sub> input can also be used for serial entry. Two control inputs, S<sub>0</sub> and S<sub>1</sub>, determine the operating mode of the shift register as shown in the Truth Table. A single buffered clock line connects all ten flip-flops which are activated on the high-to-low transition of the clock pulse. Guaranteed input clock frequency is 25MHz. With the exception of the Hold Mode, the control inputs may be changed when the clock is in either the high or low state without causing false triggering. The Hold Mode can be entered only when the clock is low. Applications for the 8274 Shift Register include Parallel-to-Serial conversion, Modem Data Transmission, Pseudo-Random Code generation and Modulo-N Frequency Division.

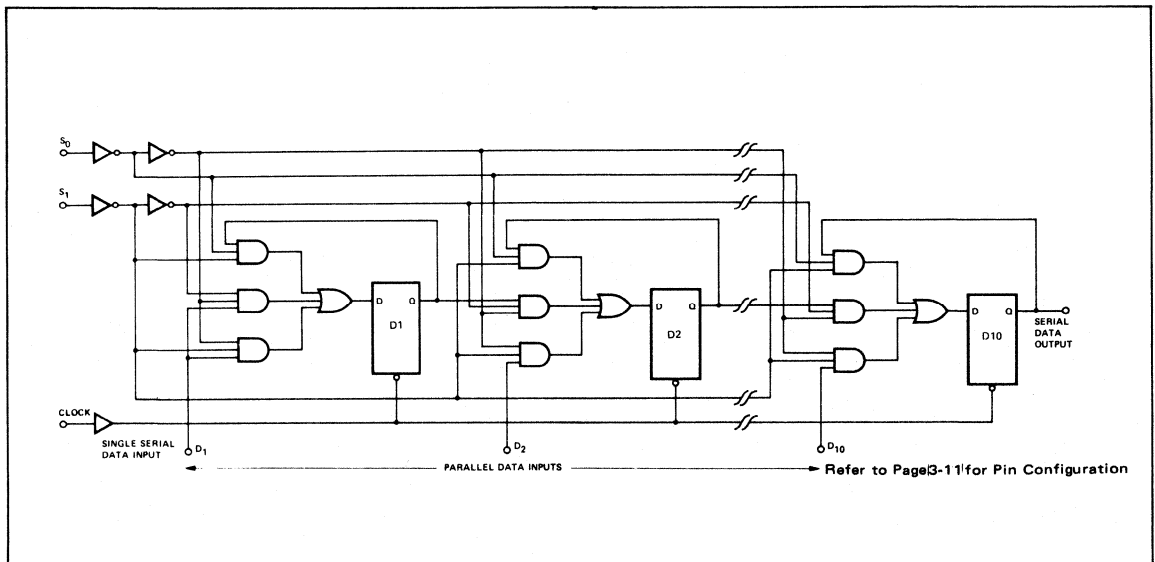
### TRUTH TABLE

S <sub>0</sub>	S <sub>1</sub>	OPERATING MODE
0	0	Hold
0	1	Clear
1	0	Load
1	1	Shift

### PIN CONFIGURATIONS (Top View)



### LOGIC DIAGRAM





**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	D <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	CLOCK	OUTPUTS	
"1" Output Voltage	2.6	3.4		V	2.0V	2.0V	2.0V	Pulse	-800μA	6
"0" Output Voltage		0.2	0.4	V	0.8V	2.0V	2.0V	Pulse	16mA	7
"0" Input Current										
D <sub>n</sub>	-0.2		-1.2	mA	0.4V					
S <sub>0</sub> and S <sub>1</sub>	-0.2		-1.2	mA		0.4V	0.4V			
Clock	-0.2		-1.6	mA				0.4V		
"1" Input Current										
D <sub>n</sub>			40	μA	4.5V					
S <sub>0</sub> and S <sub>1</sub>			40	μA		4.5V	4.5V			
Clock			40	μA				4.5V		

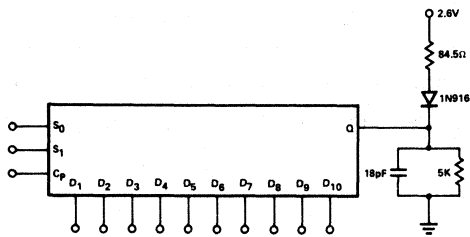
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	D <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>	CLOCK	OUTPUT	
Data Transfer Rate	25MHz	30		MHz						10
Turn-On Delay (Clock to Output)		27	40	ns						10
Turn-Off Delay (Clock to Output)		21	40	ns						10
Clock Pulse Width		15	20	ns						10
Set-Up Time (t <sub>setup</sub> )										10
D <sub>n</sub>		16	10	ns						
S <sub>0</sub> , S <sub>1</sub>		16	25	ns						
Hold Time (t <sub>hold</sub> )										
D <sub>n</sub>		2	15	ns						
S <sub>0</sub> , S <sub>1</sub>		16	25	ns						
Power Consumption/Supply Current		380/72	567/108	mW	4.5V	4.5V	4.5V	0V		8
Short Circuit Output Current	-20		-70	mA	2.0V	2.0V	2.0V	Pulse	0.0V	8,9
Input Voltage Rating	5.5			V	10mA					

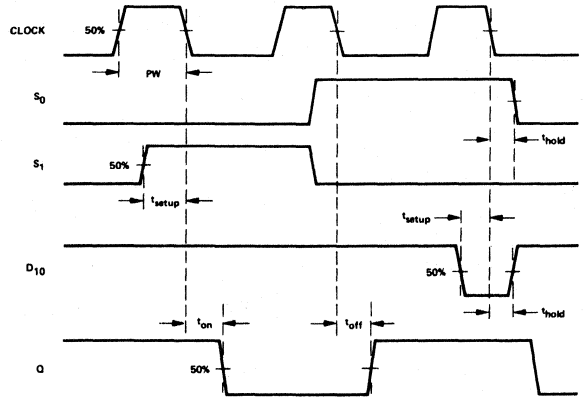
NOTES

- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>. V<sub>CC</sub> = 5.25V.
- Not more than one output should be shorted at one time.
- See AC Test Figure.

AC TEST FIGURE AND WAVEFORMS



Clock Pulse Characteristics  
 Pulse Amplitude = 3.0V  
 $t_r, t_f \leq 10\text{ns}$   
 PW  $\leq 50\text{ns}$

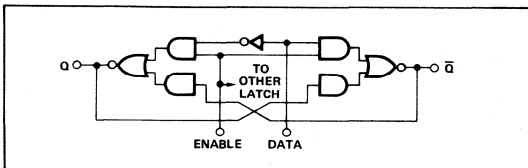


DIGITAL 8000 SERIES TTL/MSI

### DESCRIPTION

The 8275 is a QUAD LATCH circuit designed to provide temporary storage of four bits of information. A common application is as a holding register between a counter and a display driver (such as the 8280 and 8T01.) Separate enable lines to latches 1-2 and 3-4 allow individual control of each pair of latches. Initially, data is transferred on the rising edge of the enable pulse. While the enable is high, output Q follows the data input. When the enable falls, the input data present at fall time is retained at the Q output. Both Q and  $\bar{Q}$  are accessible.

### LOGIC DIAGRAM

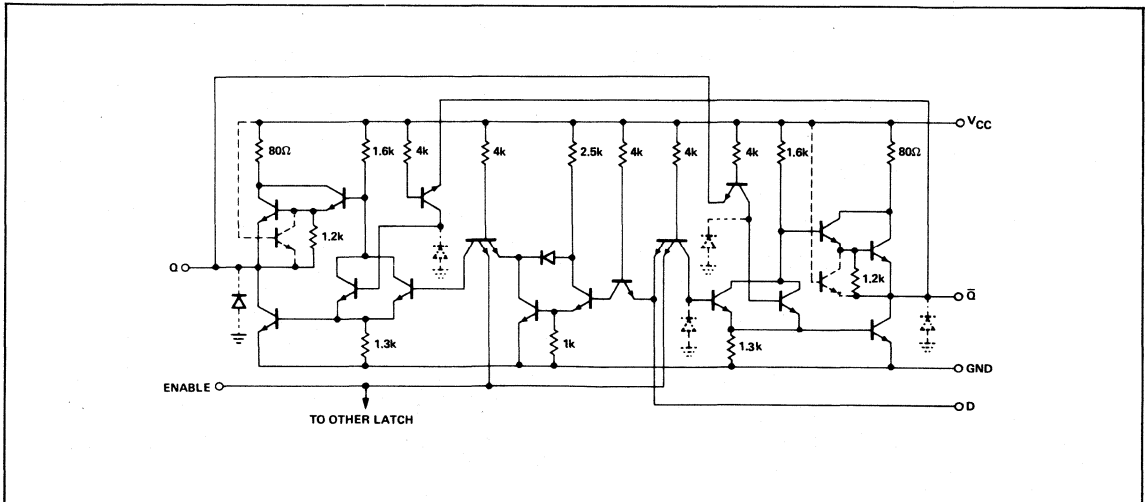


### TRUTH TABLE

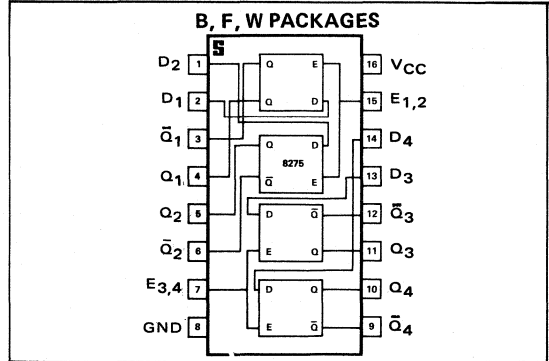
(Each Latch)			
ENABLE	DATA	Q	$\bar{Q}$
1	1	1	0
1	0	0	1
0	1	*	*
0	0	*	*

\*No Change.

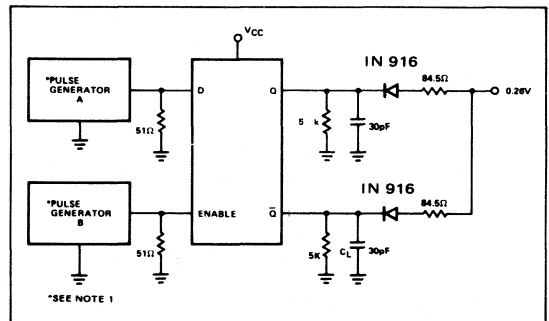
### SCHEMATIC DIAGRAM



### PIN CONFIGURATIONS (Top View)



### AC TEST FIGURE



# SIGNETICS QUAD BISTABLE LATCH ■ 8275

## ELECTRICAL CHARACTERISTICS (Over Recommended Operating Temperature And Voltage)

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	DATA INPUT	ENABLE INPUT	OUTPUTS	
"1" Output Voltage (Q, $\bar{Q}$ )	2.6	3.5		V				6, 11 7, 11
"0" Output Voltage (Q, $\bar{Q}$ )			0.4	V			-800 $\mu$ A 16mA	
"0" Input Current (Data)	-0.1		-3.2	mA	0.4V	5.25V		
"0" Input Current (Enable)	-0.1		-6.4	mA	5.25V	0.4V		
"1" Input Current (Data)			80	$\mu$ A	4.5V	0.0V		
"1" Input Current (Enable)			160	$\mu$ A	0.0V	4.5V		

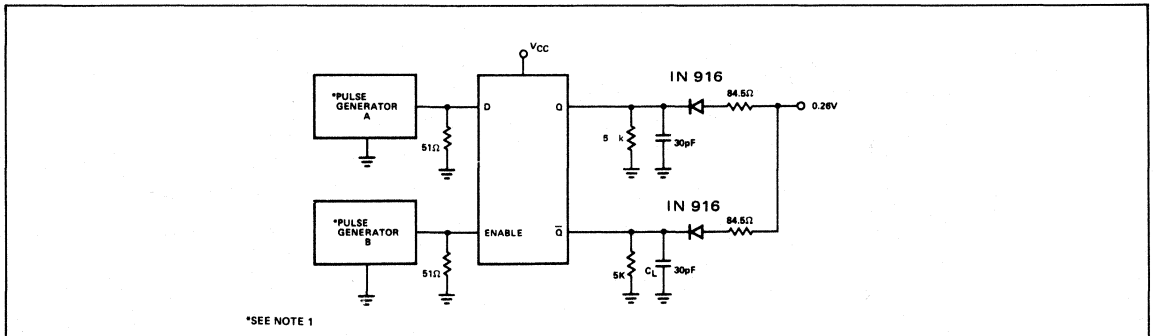
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	DATA INPUT	ENABLE INPUT	OUTPUTS	
t <sub>setup</sub> (1) at D input		12	20	ns				8, 12
t <sub>setup</sub> (0) at D input		14	20	ns				8, 12
t <sub>hold</sub> (1) at D input	0	15		ns				8, 13
t <sub>hold</sub> (0) at D input	0	6		ns				8, 13
t <sub>pd</sub> (1) D to Q		16	30	ns				8
t <sub>pd</sub> (0) D to Q		14	25	ns				8
t <sub>pd</sub> (1) D to $\bar{Q}$		24	40	ns				8
t <sub>pd</sub> (0) D to $\bar{Q}$		7	15	ns				8
t <sub>pd</sub> (1) E to Q		16	30	ns				8
t <sub>pd</sub> (0) E to Q		12	20	ns				8
t <sub>pd</sub> (1) E to $\bar{Q}$		16	30	ns				8
t <sub>pd</sub> (0) E to $\bar{Q}$		12	20	ns				8
Power Consumption/Supply Current		205/39	265/50	mW/mA				11
Input Voltage Rating (Data)	5.5			V	10mA	0.0V		9
Input Voltage Rating (Enable)	5.5			V	0.0V	10mA		
Output Short Circuit Current	-20		-70	mA	0.0V		0.0V	

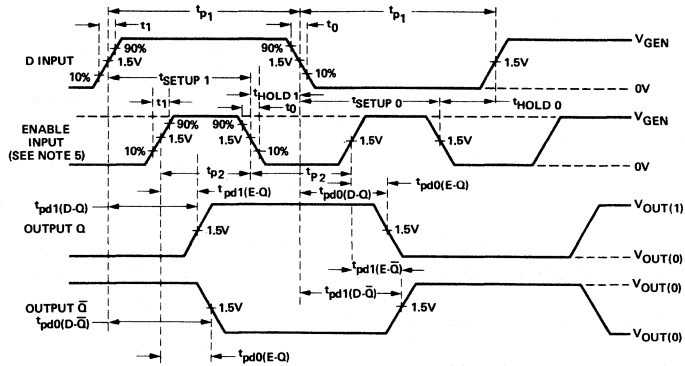
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic Definition:  
"UP" Level = "1"; "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figure.
- Not more than one output should be shorted at a time.
- Inputs for output voltage test is per TRUTH TABLE with threshold levels of 0.8V for logical "0" and 2.0V for logical "1".
- V<sub>CC</sub> = 5.25 volts.
- t<sub>setup</sub> is defined as the time prior to the fall of the clock.
- t<sub>hold</sub> is defined as the time after the fall of the clock.

### AC TEST FIGURE



AC TEST WAVEFORMS

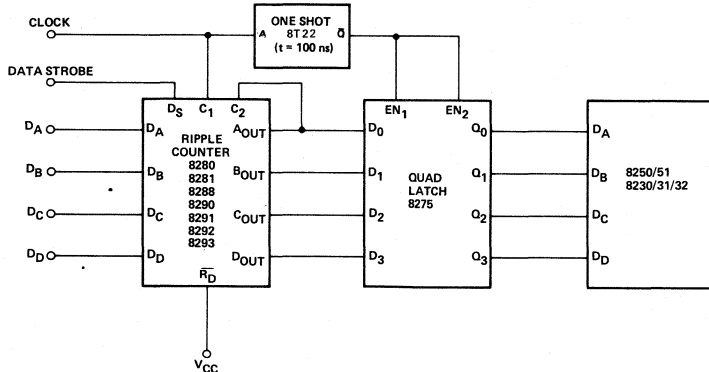


NOTES:

1. The pulse generators have the following characteristics:  $V_{gen} = 3V$ ,  $t_1 = t_0 \leq 10ns$ , and  $Z_{out} \approx 50\Omega$ . For pulse generator A,  $t_{p1} = 1\mu s$  and  $PRR = 500kHz$ . For pulse generator B,  $t_{p2} = 500ns$  and  $PRR = 1MHz$ . Positions of D-input and enable input pulses are varied with respect to each other to verify setup and hold times.
2. Each latch is tested separately.
3.  $C_L$  includes probe and jig capacitance.
4. When measuring  $t_{pd1}(D-Q)$ ,  $t_{pd0}(D-Q)$ ,  $t_{pd0}(D-\bar{Q})$ , and  $t_{pd1}(D-\bar{Q})$ , enable input must be held at logical 1.

TYPICAL APPLICATION

OUTPUT STROBING OF RIPPLE COUNTER TO ACHIEVE SYNCHRONOUS OUTPUT CHANGES



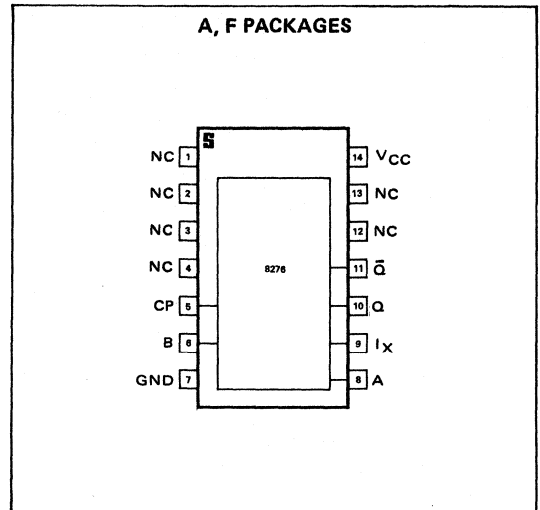
## DESCRIPTION

The 8276 is a serial-in, serial-out 8-Bit Shift Register composed of eight R-S master slave flip-flops. This shift register has input gating and an internal clock driver. In addition, a data transfer inhibit input is provided.

Data Input and Data Enable are gated through inputs A and B. An internal inverter provides the complimentary inputs to the first bit of the shift register. All inputs are fully buffered. Complementary Q and  $\bar{Q}$  outputs are provided.

The internal clock driver/inverter causes the 8276 to shift data to the output on the positive edge of the input clock pulse, making the shift register compatible with the 8825 J-K Binary and the 8828 Dual D type Binary. The register is inhibited from shifting data when the Transfer Inhibit line is high. The inhibit function is achieved by preventing data transfer from master to slave sections of the register elements when the inhibit line is used.

## PIN CONFIGURATIONS (Top View)



## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				NOTES
	MIN.	TYP.	MAX.	UNITS	DATA INPUTS	CLOCK	TRANS. INHIBIT	OUTPUTS	
"1" Output Voltage Q	2.6			V	2.0V		0.8V	-800 $\mu$ A	6, 10
"1" Output Voltage $\bar{Q}$	2.6			V	0.8V		0.8V	-800 $\mu$ A	6, 10
"0" Output Voltage Q			0.4	V	0.8V		0.8V	16mA	7, 10
"0" Output Voltage $\bar{Q}$			0.4	V	2.0V		0.8V	16mA	7, 10
"0" Input Current									
Data Input	-0.1		-1.6	mA	0.4V				
Clock Input	-0.1		-1.6	mA		0.4V			
Inhibit Input	-0.1		-1.6	mA			0.4V		
"1" Input Current									
Data Inputs			40	$\mu$ A	4.5V				
Clock Input			40	$\mu$ A		4.5V			
Inhibit Input			40	$\mu$ A			4.5V		
Input Voltage Rating	5.5			V	10mA	10mA	10mA		

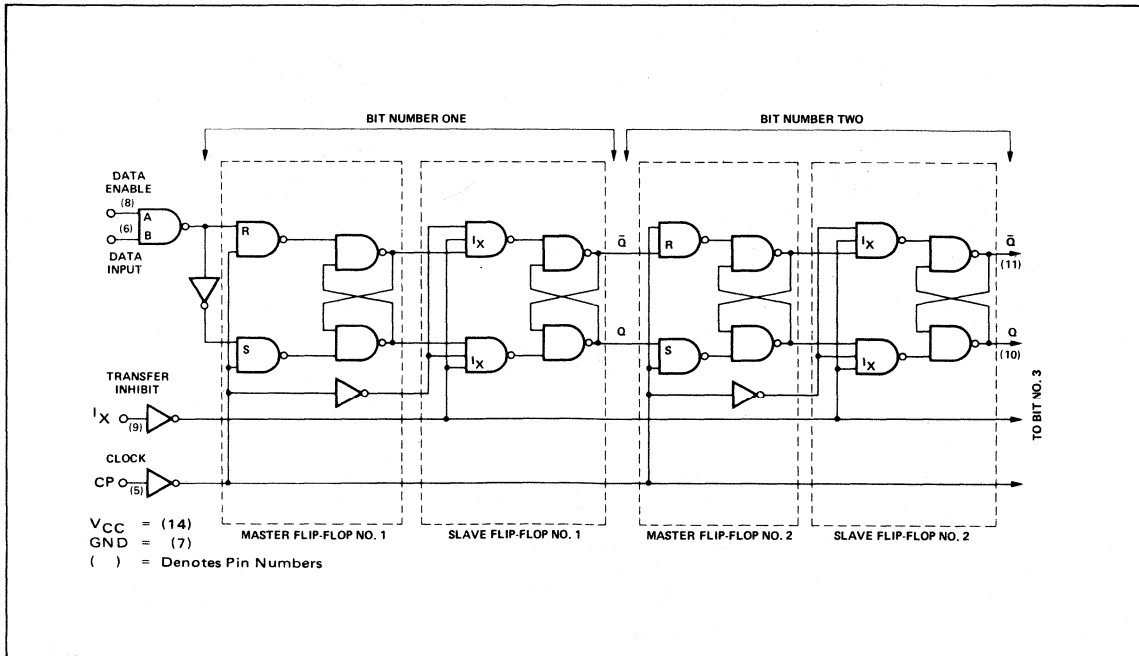
T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS				NOTES
	MIN.	TYP.	MAX.	UNITS	DATA INPUTS	CLOCK	TRANS. INHIBIT	OUTPUTS	
Power/Current Consumption		205/39	340/65	mW/mA					11
Transfer Rate	15	20		MHz					
Turn-on Delay (Clock to Output)		22	33	ns					8
Turn-off Delay (Clock to Output)		22	33	ns					8
Clock Pulse Width	25			ns					
Set Up Time (Logical) "0" at A or B Input	25			ns					8
Set Up Time (Logical) "1" at A or B Input	25			ns					8
Output Short Circuit Current	-18		-55	mA				0V	9,11

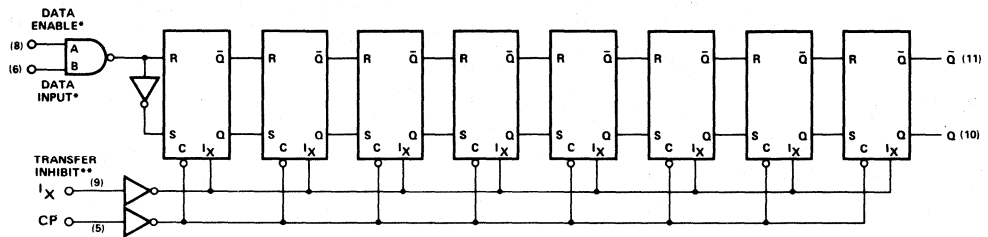
NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figure.
- Not more than one output should be shorted at one time.
- Clock input is driven by a 1kHz square wave for at least 8 cycles prior to measurements.
- V<sub>CC</sub> = 5.25V.

LOGIC DIAGRAMS



LOGIC DIAGRAM AND TRUTH TABLE (Cont'd)



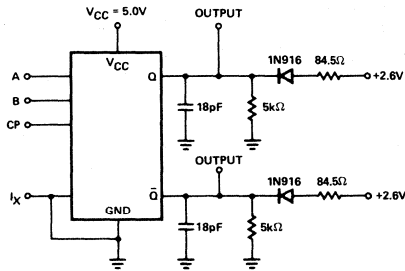
V<sub>CC</sub>=(14)  
GND=(7)  
( ) Denotes Pin Numbers

t <sub>n</sub>		t <sub>n+8</sub>
A (Data Enable)	B (Data Input)	Q
0	0	0
0	1	0
1	0	0
1	1	1

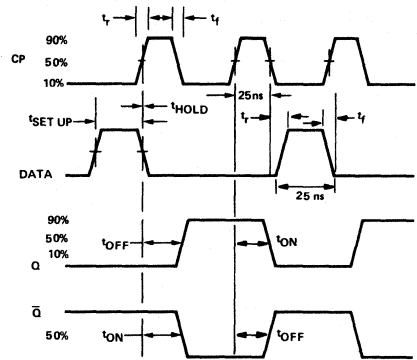
NOTES:  
t<sub>n</sub> = Bit time before clock pulse.  
t<sub>n+8</sub> = Bit time after B clock pulses.

\*NOTE: These functions are interchangeable.  
\*NOTE: Transfer Inhibit prevents transfer of data from master to slave.

AC TEST FIGURE AND WAVEFORMS

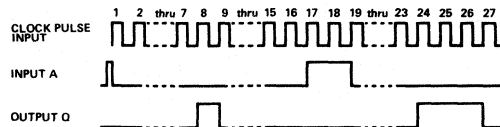


NOTES:  
1. Unused input connected to 2.6V  
2. Input pulse characteristics:  
3. Setup time = 25ns  
Hold time = 0ns  
CLOCK:  
Amplitude = 3.0V  
t<sub>r</sub> = t<sub>f</sub> = 5ns max  
PRR = 15 MHz, Pulse width = 25ns at 50% points



INPUT:  
Amplitude = 3.0V  
t<sub>r</sub> = t<sub>f</sub> = 5ns max  
PRR = 7.5 MHz  
Pulse width = 25ns at 50% point

TYPICAL INPUT/OUTPUT WAVEFORMS



NOTE: Input B is connected to 2.6V. Transfer Inhibit Connected to 0V

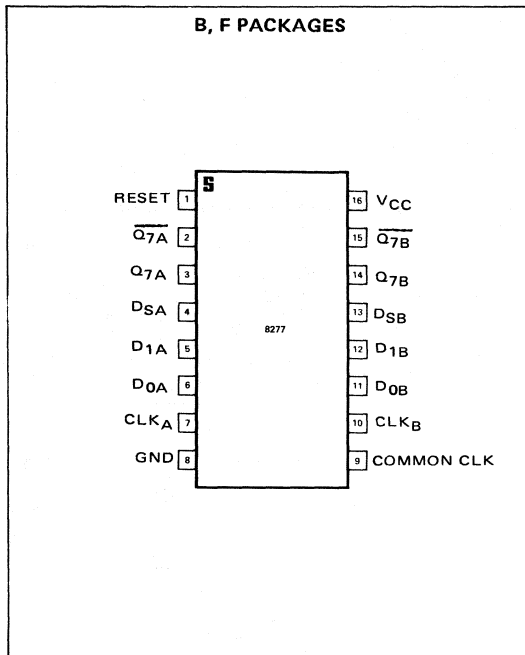


## DESCRIPTION

The 8277 is a dual 8-Bit Shift Register which provides the designer with sixteen (16) bits of serial storage operating at a typical shift rate of 20MHz. Features of the 8277 are:

1. TRUE and COMPLEMENT outputs are provided on each register's eighth bit.
2. Positive edge triggering on clock input.
3. SEPARATE CLOCK lines (pins 7 and 10) for each 8-bit register are provided as well as a COMMON CLOCK line (pin 9) for all sixteen storage bits.
4. Common RESET (pin 1).
5. AND-OR gating to the input of each 8-bit register is provided to accomplish the multiplex function.
6. Direct replacement for 9328.

## PIN CONFIGURATION (Top View)



## TRUTH TABLE

D <sub>S</sub>	D <sub>0</sub>	D <sub>1</sub>	Reset	Function
0	0	x	1	Shift in "0"
0	1	x	1	Shift in "1"
1	x	0	1	Shift in "0"
1	x	1	1	Shift in "1"
x	x	x	0	Reset "Q" to "0"

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	DATA D <sub>1</sub> , D <sub>0</sub>	DATA SELECT	CLK COMMON	CLK SEP	RESET	OUTPUTS	
"1" Output Voltage (Q)	2.6	3.5		V	2.0V	2.0V	Pulse	0.8V	2.0V	-800μA	6
"1" Output Voltage (Q)	2.6	3.5		V	0.8V	2.0V	0.8V	Pulse		-800μA	6
"0" Output Voltage (Q)			0.4	V	0.8V	0.8V	Pulse	0.8V		16mA	7
"0" Output Voltage (Q)			0.4	V	2.0V	0.8V	Pulse	0.8V		16mA	7
"0" Input Current											
Data, Reset	-0.1		-1.6	mA	0.4V				0.4V		
Data Select	-0.1		-3.2	mA		0.4V					
Clock Separate	-0.1		-1.6	mA				0.4V			
Clock Common	-0.1		-3.2	mA			0.4V				
"1" Input Current											
Data, Reset, Clock Separate			40	μA	4.5V			4.5V	4.5V		
Data Select			80	μA		4.5V					
Clock Common			80	μA			4.5V				
Power/Current Consumption			540/103	mW/mA							8
Input Voltage Rating											
All Inputs	5.5			V	10mA	10mA	10mA	10mA	10mA		

# SIGNETICS DUAL 8-BIT SHIFT REGISTER ■ 8276

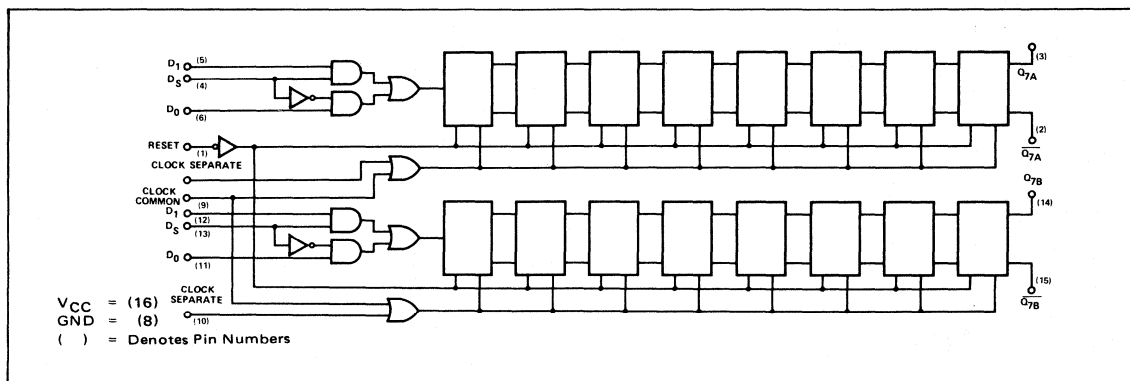
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	DATA $D_1, D_0$	DATA SELECT	CLK COMMON	CLK SEP	RESET	OUTPUTS	
Turn-on Delay											
Clock To Output		25	40	ns							10
Reset To Output		25	40	ns							10
Turn-off Delay											
Clock To Output		25	40	ns							10
Reset To Output		25	40	ns							10
Clock Pulse Width	15			ns							10
Shift Rate		20		MHz							10
Data Set-up Time		20	30	ns							10
Data Hold Time			5	ns							10

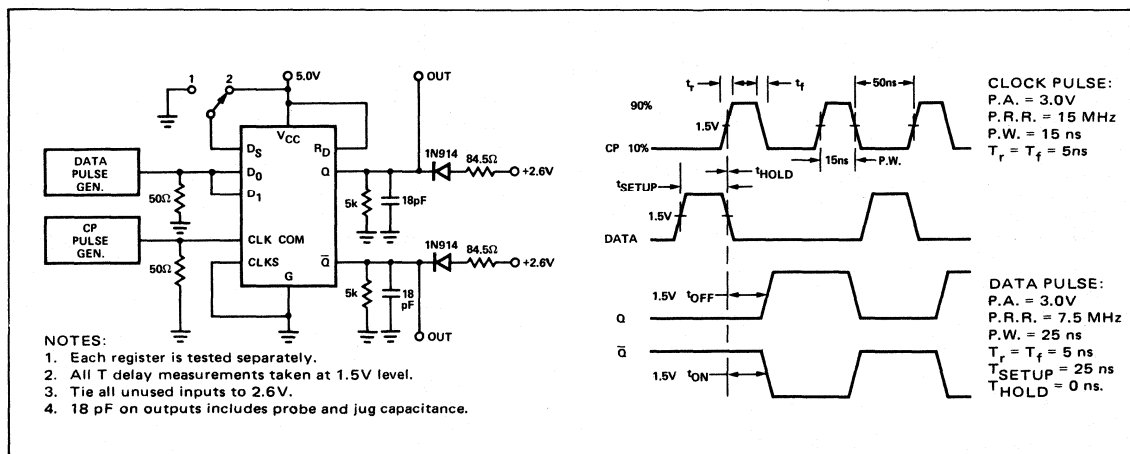
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive Logic Definitions: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- $V_{CC} = 5.25\text{V}$
- Clock input is driven by a 1 kHz square wave for at least 8 cycles prior to measurement.
- Refer to AC Test Figure.

### LOGIC DIAGRAM

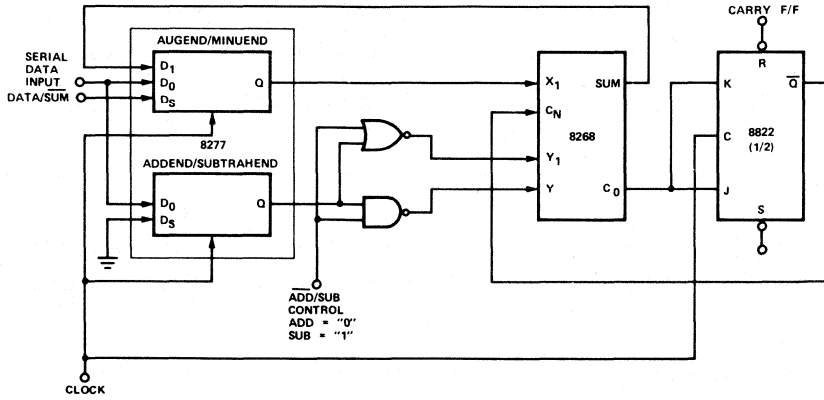


### AC TEST FIGURE AND WAVEFORMS



TYPICAL APPLICATION

8-BIT SERIAL ADD/SUBTRACTOR



### DIGITAL 8000 SERIES TTL/MSI

#### DESCRIPTION

The 8280 Decade Counter and 8281 16-State Binary Counter are four-bit subsystems providing a wide variety of counter/storage register applications with a minimum number of packages.

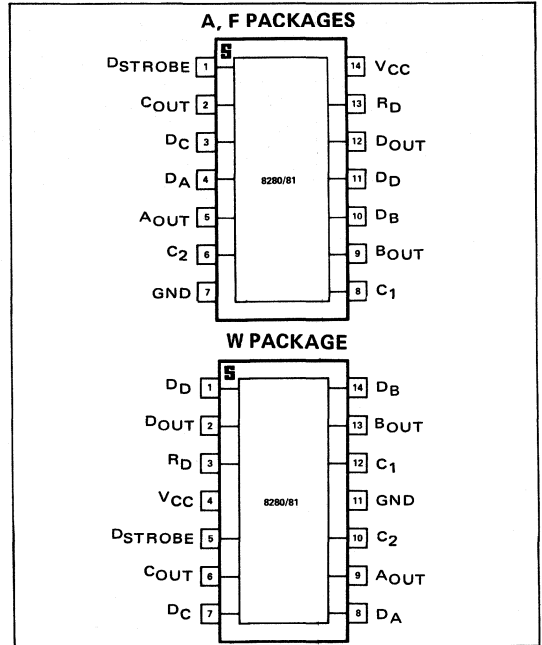
The 8280 Decade Counter can be connected in the familiar BCD counting mode, in a divide-by-two and divide-by-five configuration or in the Bi-Quinary mode. The Bi-Quinary mode produces a square wave output which is particularly useful in frequency synthesizer applications.

The 8281 Binary Counter may be connected as a divide-by-two, eight, or sixteen counter.

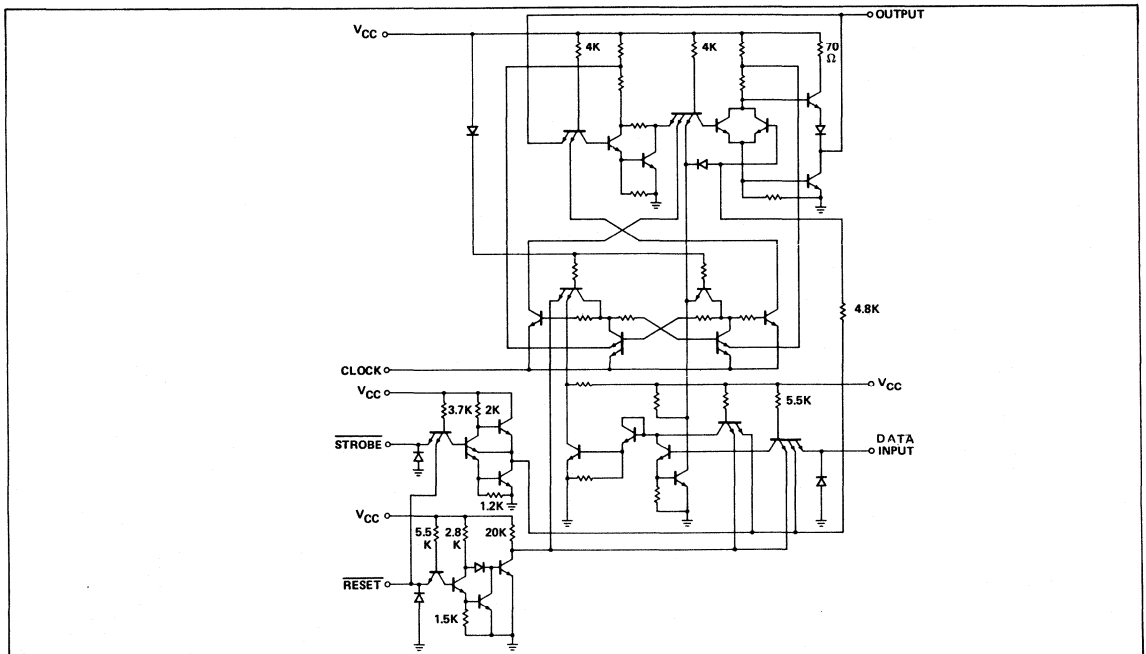
Both devices have strobed parallel-entry capability so that the counter may be set to any desired output state. A "1" or "0" at a data input will be transferred to the associated output when the strobe input is put at the "0" level. For additional flexibility, both units are provided with a reset input which is common to all four bits. A "0" on the reset line produces "0" at all four outputs.

The counting operation is performed on the falling (negative-going) edge of the input clock pulse, however there is no restriction on the transition time since the individual binaries are level-sensitive.

#### PIN CONFIGURATION (Top View)



#### SCHEMATIC DIAGRAM



**SIGNETICS BCD DECADE/4-BIT BINARY COUNTER STORAGE ELEMENT ■ 8280/81**

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
"1" Output Voltage (All Outputs)	2.6	3.5		V	0.8V	2.0V	2.0V			Output A	-800μA	7
"0" Output Voltage (All Outputs)			0.4	V	0.8V	0.8V	0.8V			Output A	16mA	8
"0" Input Current Strobe	-0.1		-1.6	mA	0.4V							
Data Inputs	-0.1		-1.2	mA		0.4V						
Reset	-0.1		-3.2	mA			0.4V					
Clock 1	-0.1		-3.2	mA				0.4V				
Clock 2 (8280)	-0.1		-3.2	mA					0.4V			
Clock 2 (8281)	-0.1		-1.6	mA					0.4V			
"1" Input Current Strobe			40	μA	4.5V							
Data Inputs			40	μA		4.5V						
Reset			80	μA			4.5V					
Clock 1			80	μA				4.5V				
Clock 2 (8280)			80	μA					4.5V			
Clock 2 (8281)			40	μA					4.5V			
Power/Current Consumption		184/35	236/45	mW/mA			0V	0V	0V			12
Input Voltage Rating all Inputs	5.5			V	10mA	10mA	10mA	10mA	10mA			10
Output Short Circuit Current	-10		-60	mA	0V					0V		9, 12

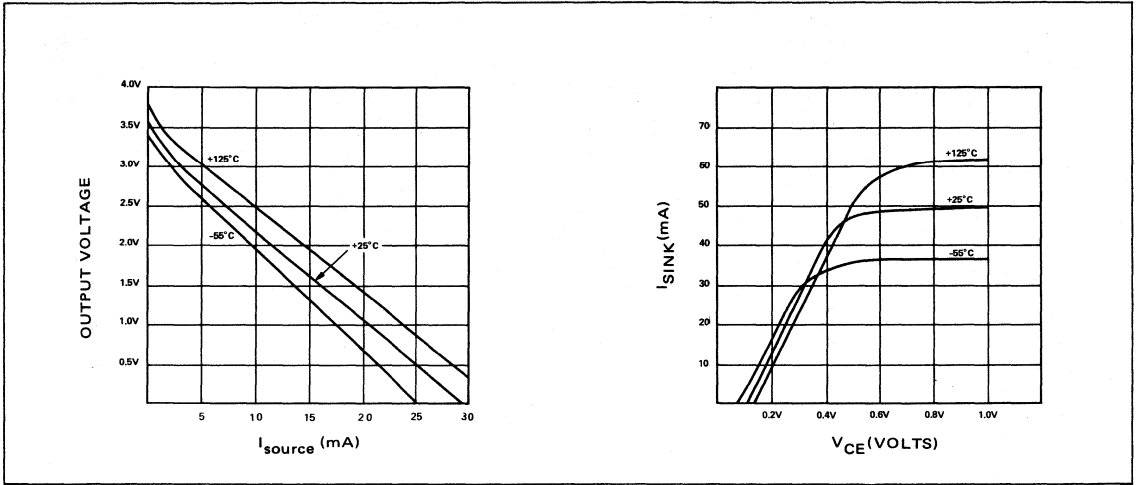
**T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V**

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
Clock Mode t <sub>on</sub> Delay Bit A, B, C, D		15	25	ns								11
Clock Mode t <sub>off</sub> Delay Bit A, B, C, D		15	25	ns								11
Data/Strobe t <sub>on</sub> Delay Bit A, B, C, D		25	35	ns								11
Data/Strobe t <sub>off</sub> Delay Bit A, B, C, D		30	40	ns								11
Toggle Rate	20	25		MHz								11
Strobe Pulse Width		20	35	ns						A <sub>OUT</sub>		11
Reset Pulse Width		20	35	ns						A <sub>OUT</sub>		11
Strobe Release Time		30	40	ns						A <sub>OUT</sub>		11
Reset Release Time		50	75	ns						A <sub>OUT</sub>		11

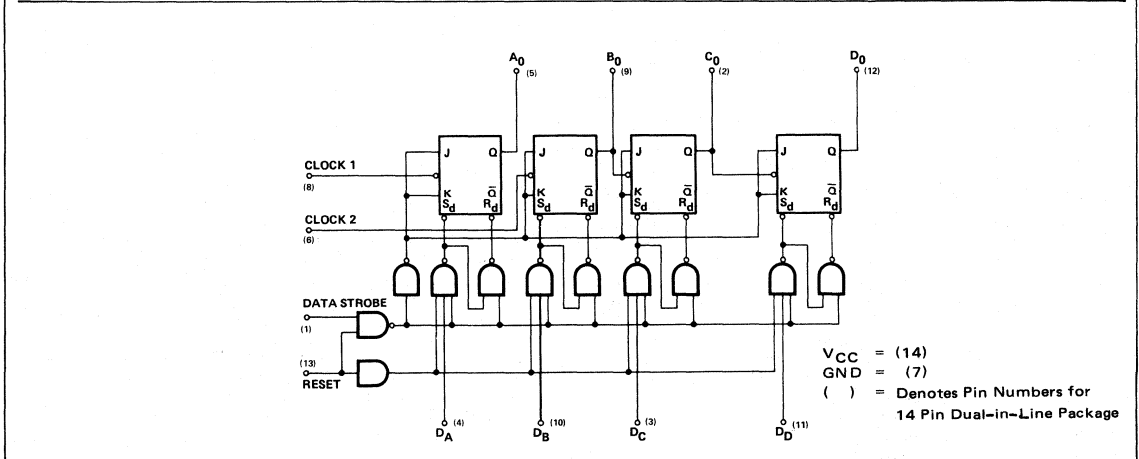
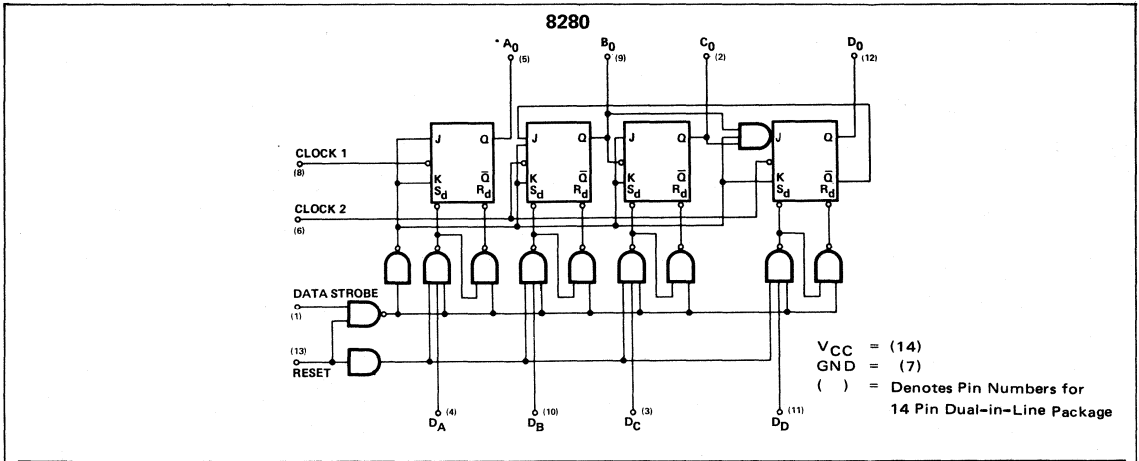
**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Measurements apply to each output and the associated data input independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Not more than one output should be shorted at a time.
- Each input is tested separately.
- Refer to AC Test Figures.
- V<sub>CC</sub> = 5.25V.

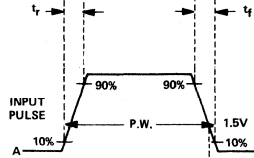
TYPICAL OUTPUT CHARACTERISTICS



LOGIC DIAGRAMS

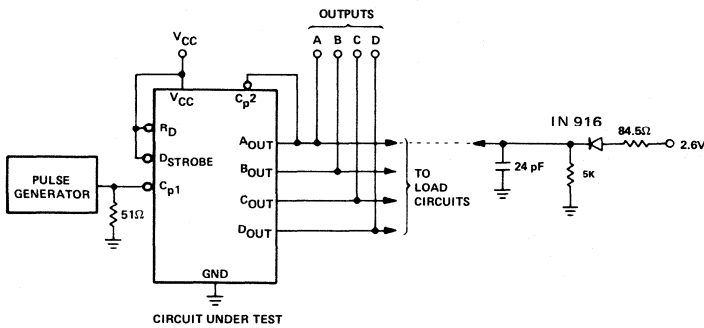


AC TEST FIGURES AND WAVEFORMS



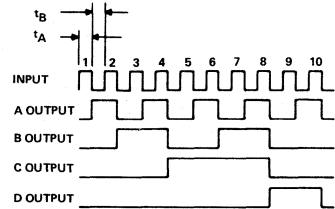
NOTE: Input pulse notations apply unless otherwise specified.

TOGGLE RATE

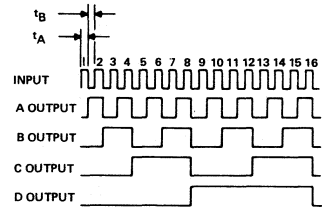


INPUT PULSE:  
Amplitude = 2.6V  
 $t_A = 25ns$ ,  $t_B = 25ns$ ,  
 $t_r = t_f = 5ns$  max.

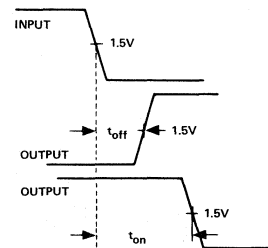
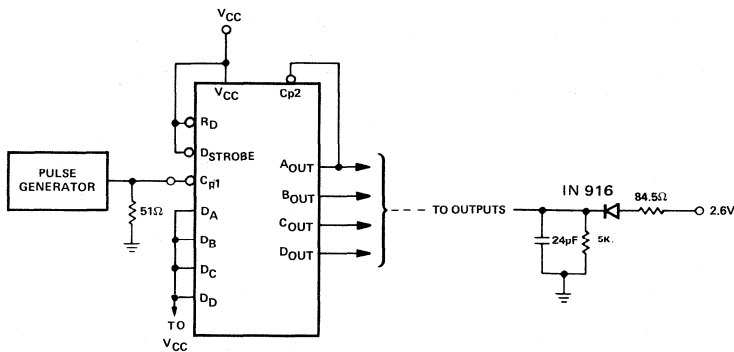
8280



8281



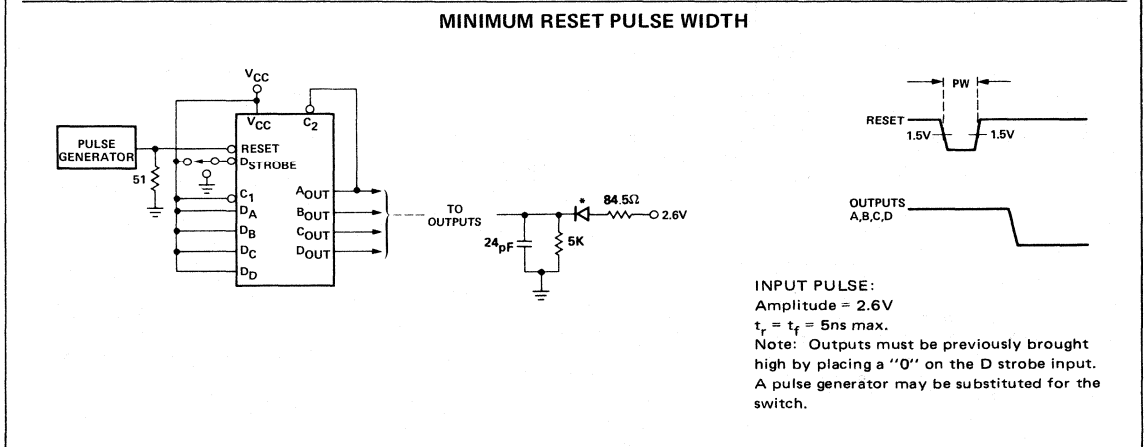
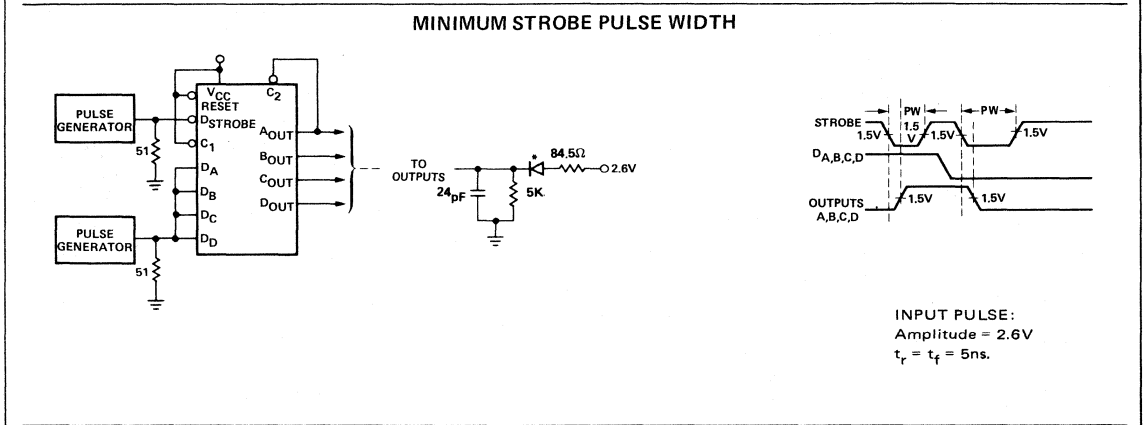
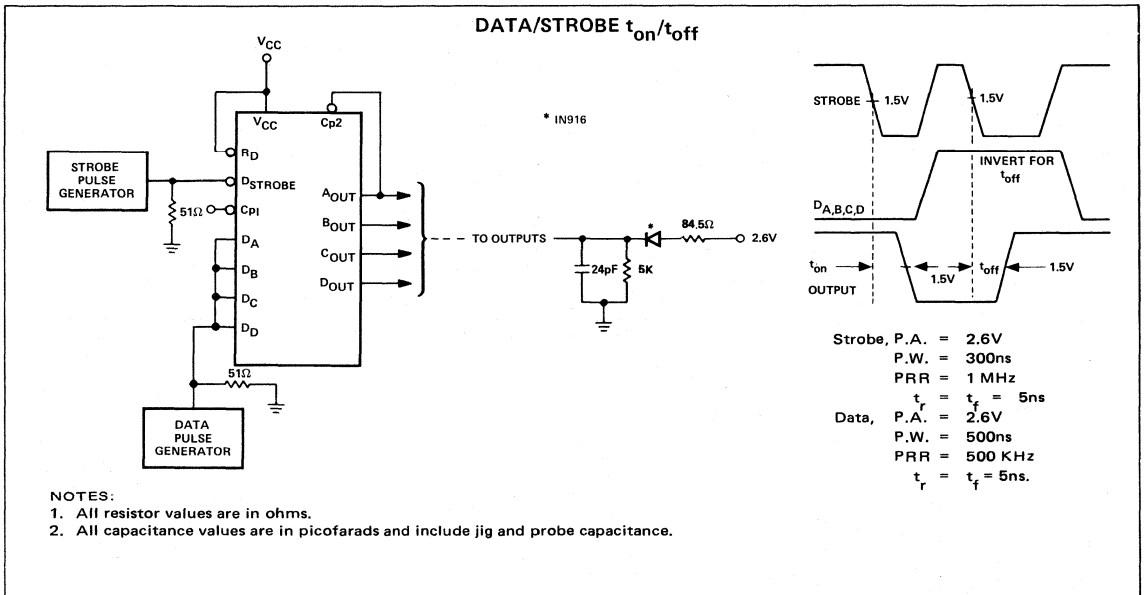
CLOCK MODE  $t_{on}/t_{off}$  DELAY



- $t_{on}$  and  $t_{off}$  are measured from the clock input of each binary to the Q output of that binary.
- Each Q output will be loaded with a load circuit as shown.

INPUT PULSE:  
Amplitude = 2.6V  
P.W. = 30ns  
 $t_r = t_f = 5ns$ .

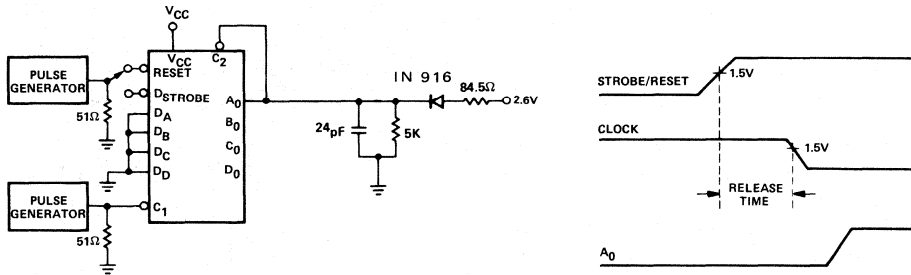
AC TEST FIGURES AND WAVEFORMS (Cont'd)





AC TEST FIGURES AND WAVEFORMS (Cont'd)

STROBE/RESET RELEASE TIME



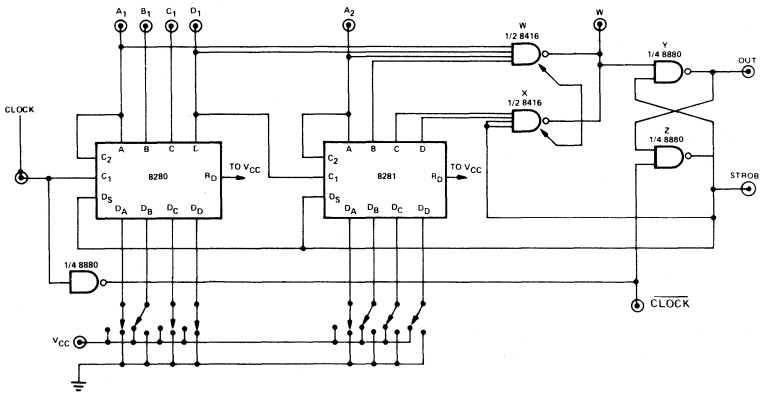
NOTES:

1. All resistor values are in ohms.
2. All capacitance values are in picofarads and include jig and probe capacitance.

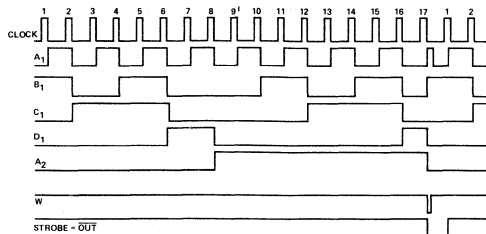
Clock, Strobe/Reset:  
 Ampl = 2.6V  
 tr = tf = 5 ns max.  
 PRR = 1 MHz 50% Duty Cycle.

TYPICAL APPLICATIONS

VARIABLE MODULUS COUNTER



TIMING DIAGRAM



#### DESCRIPTION

The Up/Down Counter is a monolithic MSI circuit containing gates and binaries interconnected to provide a bi-directional divide-by-ten (decade) or divide-by-sixteen (hexadecimal) result as a function of the clock input.

The output code of the decade up/down counter is the commonly used BCD (8421) code, and the output sequence generated is the binary equivalent of the decimal numbers 0 through 9.

The hexadecimal up/down counter provides the output sequence 0 through 15 which is presented in a weighted binary code (8421).

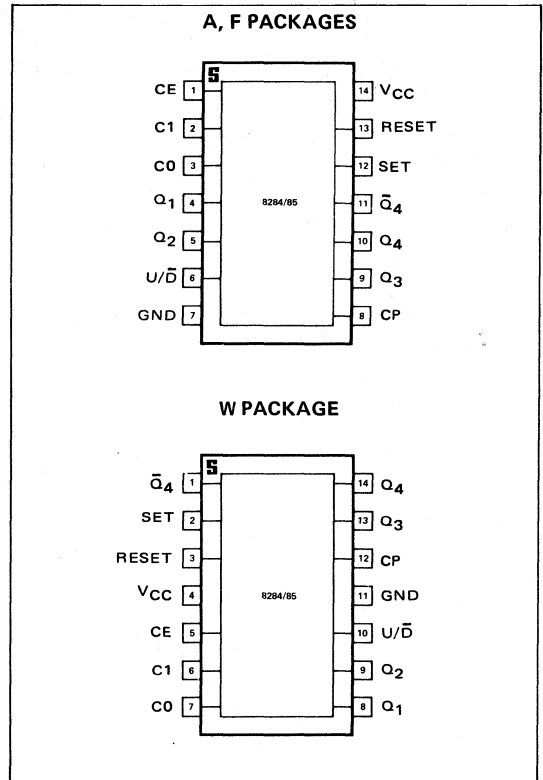
Set and Reset on the binary elements provide asynchronous entry with respect to the clock line, causing a count of "0" or "15" (8284) or of "0" or "9" (8285), and also inhibit propagation of count enable data.

Entry and propagation of data is performed in a synchronous manner with the clock line, which is active on its negative going excursion. The input from a previous stage or other source is channeled through "Carry In" and its propagation can be inhibited by the "Count Enable" line. "Carry In" and "Count Enable" input duality gives added flexibility in multiple package cascading applications.

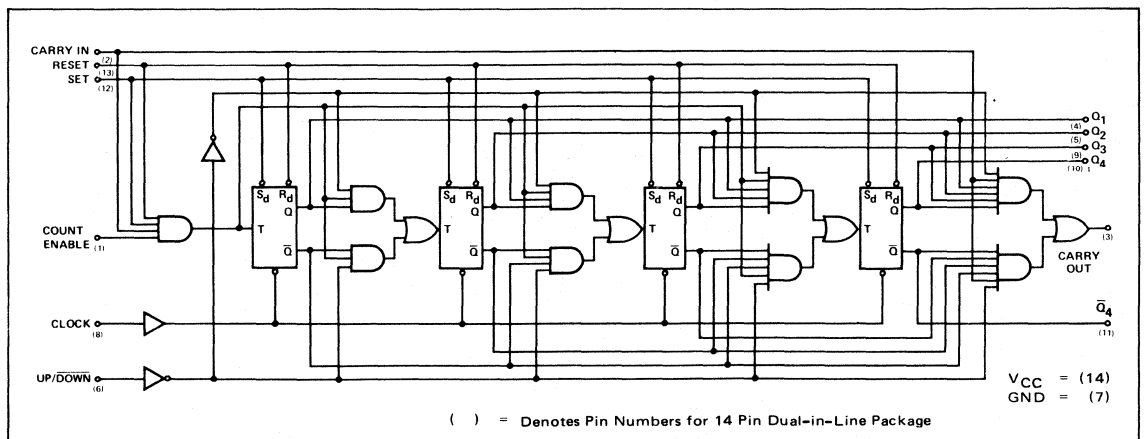
Direction of the counter is steered from a single line (Up/Down), where a "0" level will cause a "down" count and a "1" level will accomplish an "up" count.

In addition to all Q outputs of the four binaries the  $\bar{Q}_4$  output of the most significant binary (Q4) and the Carry Out term are available.

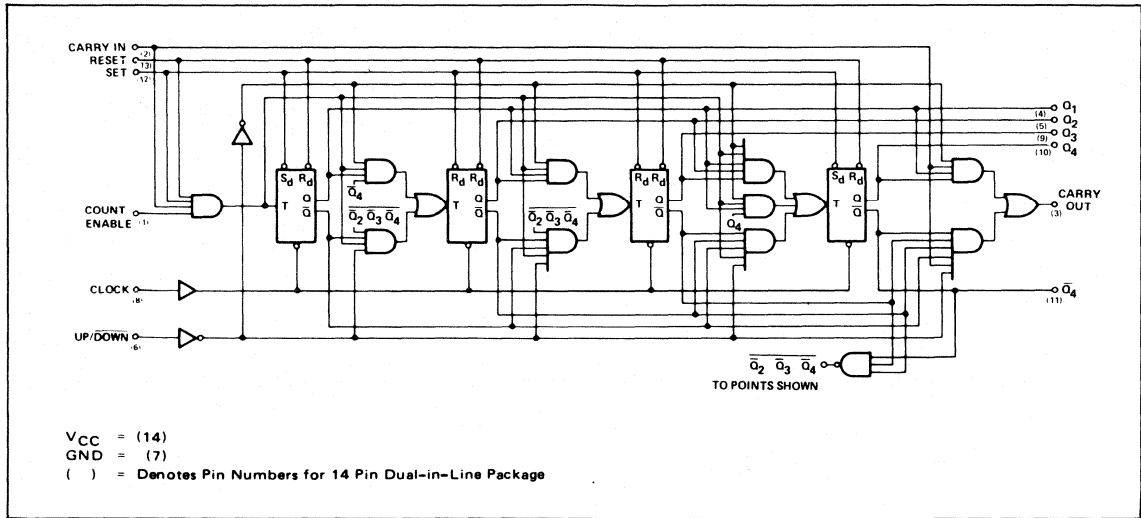
#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM



LOGIC DIAGRAMS (Cont'd)



ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS							NOTES
	MIN.	TYP.	MAX.	UNITS	SET	RESET	UP/DOWN	COUNT ENABLE	CLOCK	CARRY IN	OUTPUTS	
"1" Output Voltage Q <sub>1</sub> , Q <sub>4</sub> , Carry Out	2.6			V	0.8V	2.0V	2.0V			2.0V	-800μA	5
Q <sub>2</sub> , Q <sub>3</sub> , (8284)				V			0.8V				-800μA	5, 9
Q <sub>2</sub> , Q <sub>3</sub> (8285)	2.6			V	Pulse						-800μA	5
Q <sub>4</sub>	2.6			V	2.0V	0.8V					-800μA	5
"0" Output Voltage Q <sub>1</sub> , Q <sub>2</sub> , Q <sub>3</sub> , Q <sub>4</sub> and Carry Out			0.4	V	2.0V	0.8V				0.8V	9.6mA	6
Q <sub>4</sub>			0.4	V	0.8V	2.0V					9.6mA	6
"1" Input Current				μA								
Carry In			120	μA	Pulse		5.0V			4.5V		
Set			200	μA	4.5V	Pulse						
Reset			40	μA	Pulse	4.5V						
Count Enable			40	μA				4.5V				
Clock and Up/Down			40	μA			4.5V		4.5V			
"0" Input Current				mA								
Carry In	-0.1	-3.2		mA	Pulse		0V			0.4V		
Set	-0.1	-6.4		mA	0.4V							
Reset	-0.1	-1.6		mA		0.4V						
Count Enable	-0.1	-1.6		mA			0.4V					
Clock	-0.1	-1.6		mA				0.4V				
Up/Down	-0.1	-1.6		mA			0.4V		0.4V			
Input Voltage Rating				V								
Carry In	5.5			V		0V	5.0V	0V		10mA		
Reset	5.5			V		10mA		0V				
Set	5.5			V	10mA			0V				
Count Enable	5.5			V	0V			10mA				
Up/Down	5.5			V			10mA					
Output Short Circuit Current	-20		-70	mA							0V	8, 10

T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS							NOTES
	MIN.	TYP.	MAX.	UNITS	SET	RESET	UP/DOWN	COUNT ENABLE	CLOCK	CARRY IN	OUTPUTS	
Power/Current Consumption		315/	420/	mW/								10
Propagation Delay		60	80	ns								
t <sub>on</sub> Clock to Q <sub>4</sub> & $\bar{Q}_4$		32	45	ns								7
t <sub>on</sub> Clock to Q <sub>1</sub> , Q <sub>2</sub> , Q <sub>3</sub>		28	40	ns								7
t <sub>off</sub> Clock to Q <sub>n</sub> , $\bar{Q}_n$		25	35	ns								7
t <sub>on</sub> Reset to Q <sub>n</sub>		24	35	ns								7
t <sub>off</sub> Set to Q <sub>n</sub>		15	25	ns								7
t <sub>on</sub> Reset to $\bar{Q}_n$		32	45	ns								7
t <sub>on</sub> Carry In to Carry Out		15	25	ns								7
t <sub>off</sub> Carry In to Carry Out		20	30	ns								7
Clock Min. "1" Interval	20	15		ns								7
Count Rate	20	30		MHz								
Carry In, Count Enable, & Up/Down Set-Up Time		15	25	ns								
Carry In, Count Enable & Up/Down Hold Time		0	2	ns								
Set/Reset Pulse Width		20	25	ns								

NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive NAND Logic Definition: "UP" Level = "1", "DOWN" Level = "0".
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figure.
- Not more than one output should be shorted at a time.
- Connect Q<sub>4</sub> to count enable, set the counter (1001), and count down. The counter will halt at BCD-7 (0111).
- V<sub>CC</sub> = 5.25 volts. [

AC TEST FIGURES AND WAVEFORMS

**MODE OF OPERATION**

8284 Binary Synchronous Up/Down Counter  
8285 BCD Synchronous Up/Down Counter

	SET	RESET	CARRY IN	COUNT ENABLE	UP/DOWN	FUNCTION
A. Asynchronous						
8284 Only	1	0	X	X	X	"0" (0 0 0 0)
8285 Only	0	1	X	X	X	"15" (1 1 1 1)
	0	1	X	X	X	"9" (1 0 0 1)
B. Synchronous						
	1	1	0	X	X	Hold *
	1	1	X	0	X	Hold *
	1	1	1	1	0	"Down" Count *
	1	1	1	1	1	"Up" Count *

\*Function is synchronous with NEGATIVE going transition of the Clock pin.  
X = don't care.

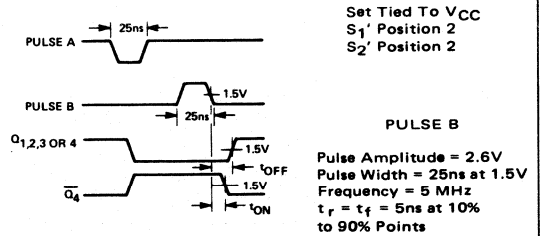
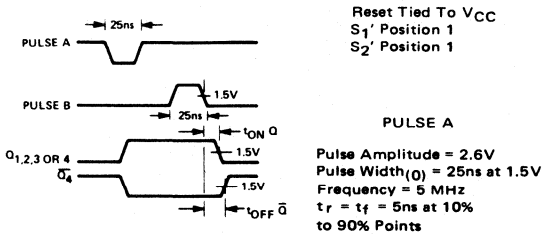
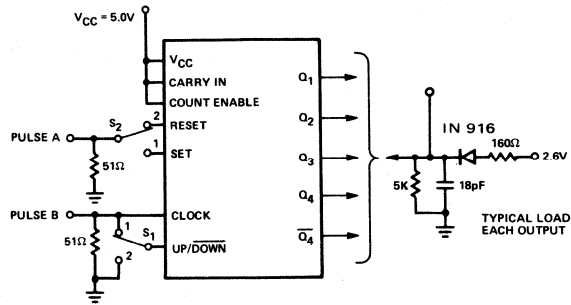
**CARRY OUT**

Carry Out<sub>8284</sub> = Carry In (Q<sub>1</sub> Q<sub>2</sub> Q<sub>3</sub> Q<sub>4</sub> UP +  $\bar{Q}_1 \bar{Q}_2 \bar{Q}_3 \bar{Q}_4$  DOWN)

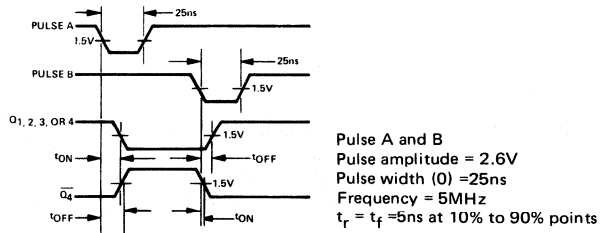
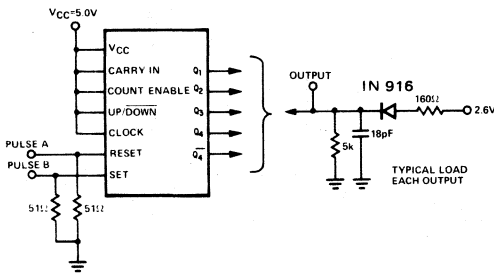
Carry Out<sub>8285</sub> = Carry In (Q<sub>1</sub> Q<sub>4</sub> UP +  $\bar{Q}_1 \bar{Q}_2 \bar{Q}_3 \bar{Q}_4$  DOWN)

AC TEST FIGURES AND WAVEFORMS (Cont'd)

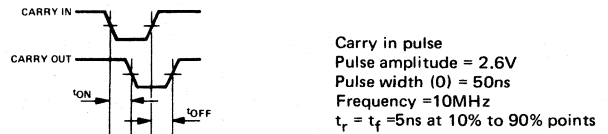
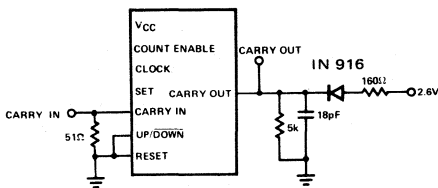
CLOCK MODE ( $t_{on}$  AND  $t_{off}$ )



SET/RESET MODE ( $t_{on}$  and  $t_{off}$ )

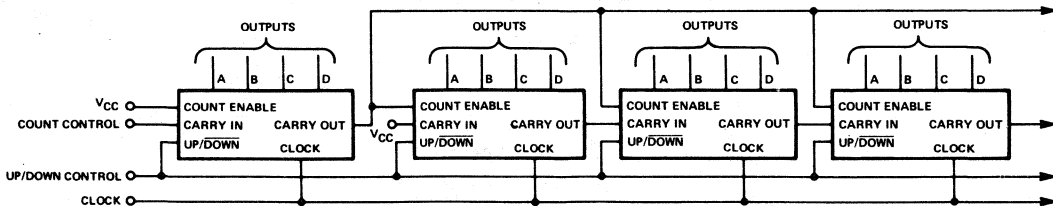


CARRY IN/CARRY OUT ( $t_{on}$  and  $t_{off}$ )



TYPICAL APPLICATIONS

SYNCHRONOUS EXPANSION UP/DOWN COUNTERS



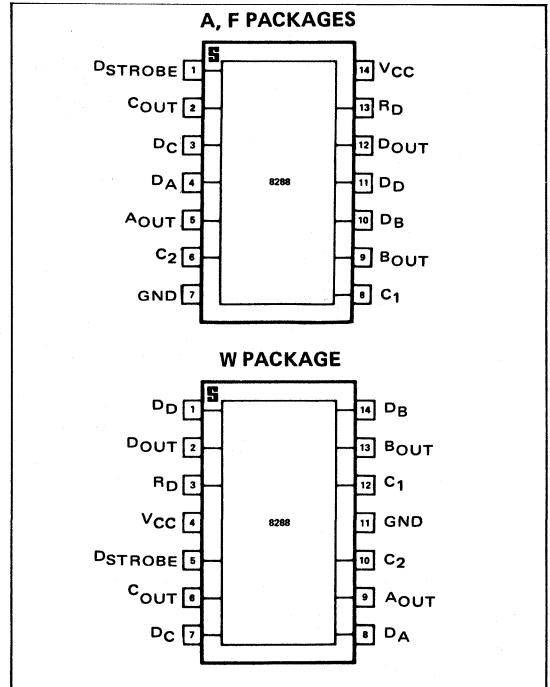
### DESCRIPTION

The 8288 Divide by Twelve Counter is a four-bit subsystem consisting of divide by two and divide by six counters in a 14 pin package. For Divide-by-Twelve operation, output A is connected externally to the clock 2 input.

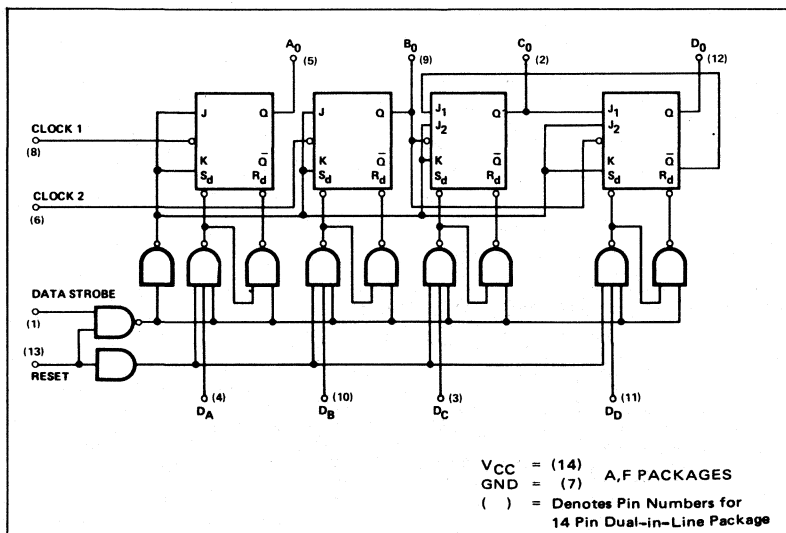
The 8288 has strobed paralleled data entry capability so that the counter may be preset to any desired output state. A "1" or "0" at a data input will be transferred to the associated output when the strobe input is put at a "0" level. For additional flexibility, the 8288 is provided with a common reset. A "0" on the reset line produces "0" at all four outputs.

The counting operation is performed on the falling (negative going) edge of the input clock pulse, however, there is no restriction on transition time since the individual binaries are level sensitive. The data strobe and reset functions are asynchronous with respect to the clock.

### PIN CONFIGURATION (Top View)



### LOGIC DIAGRAM



### TRUTH TABLE\*

Count	OUTPUT			
	D	C	B	A
0	0	0	0	0
1	0	0	0	1
2	0	0	1	0
3	0	0	1	1
4	0	1	0	0
5	0	1	0	1
6	0	1	1	0
7	0	1	1	1
8	1	0	0	0
9	1	0	0	1
10	1	0	1	0
11	1	0	1	1

\*Connected for Divide-by-Twelve operation (output A connected to CP2)

**SIGNETICS DIVIDE-BY-TWELVE COUNTER/STORAGE ELEMENT ■ 8288**

**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
"1" Output Voltage	2.6	3.5		V	0.8V	2.0V	2.0V					6, 7
"0" Output Voltage			0.4V	V	0.8V	0.8V	0.8V			Output A	-800μA	6, 8
"0" Input Current										Output A	16mA	
Data Strobe	-0.1		-1.6	mA	0.4V		5.25V					
Data Inputs	-0.1		-1.2	mA		0.4V						
Reset	-0.1		-3.2	mA	5.25V		0.4V					
Clock 1	-0.1		-3.2	mA				0.4V				
Clock 2	-0.1		-1.6	mA					0.4V			
"1" Input Current												
Data Strobe			40	μA	4.5V		0V					
Data Input			40	μA		4.5V						
Reset			80	μA			4.5V					
Clock 1			80	μA				4.5V				
Clock 2			80	μA					4.5V			
Power/Current Consumption		184/35	236/45	mW/mA			0V	0V	0V			11
Input Voltage Rating												
Data Strobe	5.5			V	10mA							
Data Inputs	5.5			V		10mA						
Reset	5.5			V			10mA					
Output Short Circuit Current	-10		-60	mA	0V						0V	10, 11

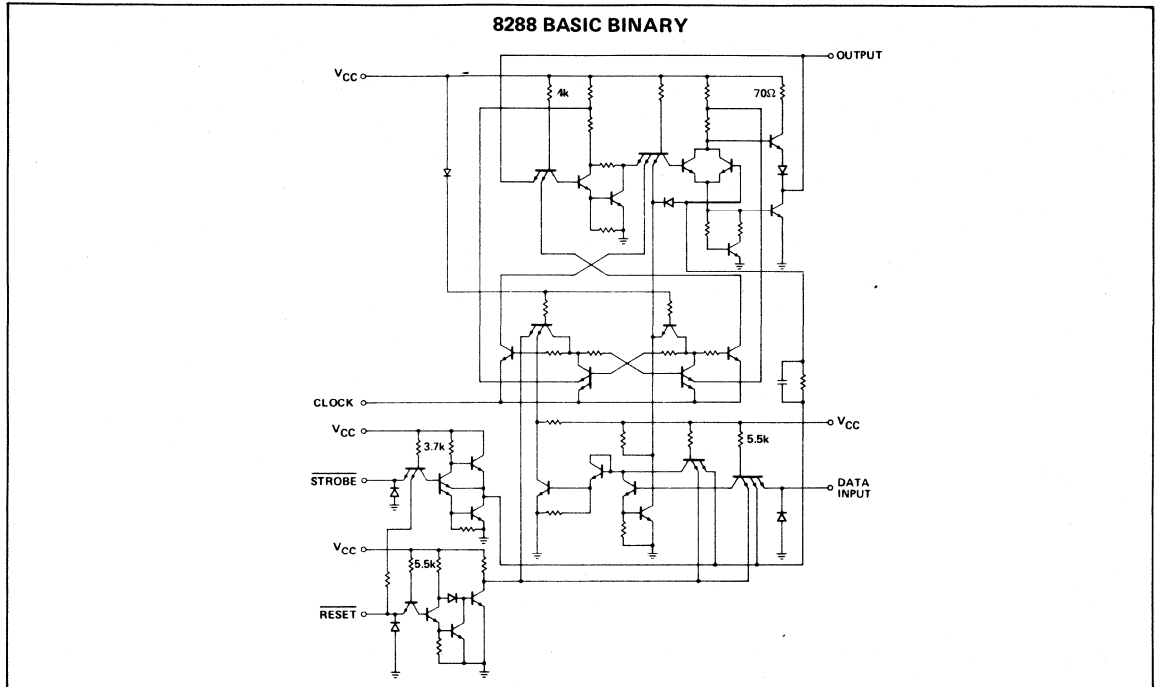
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
Clock Mode $t_{on}$ Delay		15	25	ns								9
Bit A, B, C, D												
Clock Mode $t_{off}$ Delay		15	25	ns								9
Bit A, B, C, D												
Data/Strobe $t_{on}$ Delay		20	35	ns								9
Bit A, B, C, D												
Data/Strobe $t_{off}$ Delay		25	40	ns								9
Bit A, B, C, D												
Toggle Rate	20	25		MHz								9
Strobe Hold Time		25	35	ns		0.8V	2.0V	2.0V		Output A		
Reset Hold Time		20	35	ns	2.0V	0.8V		2.0V		Output A		
Strobe Release Time		30	40	ns								
Reset Release Time		50	75	ns								

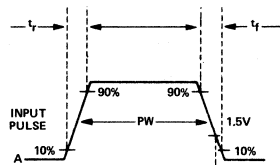
**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each output and the associated data input independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ . Refer to AC Test Figures.
- Not more than one output should be shorted at a time.
- $V_{CC} = 5.25$  volts.

**SCHEMATIC DIAGRAM**

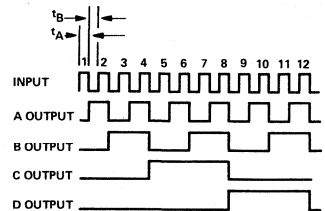
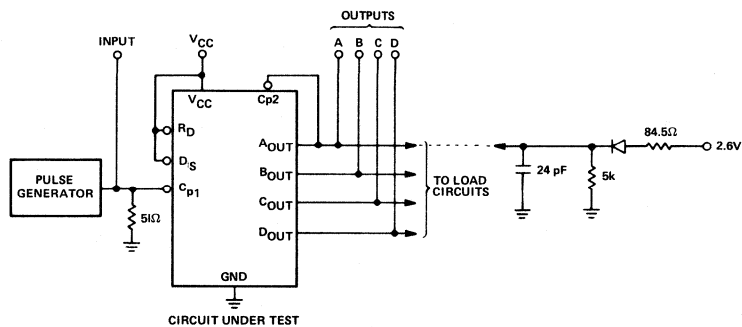


**AC TEST FIGURES AND WAVEFORMS**



NOTE: Input pulse notations apply unless otherwise specified.

**TOGGLE RATE**

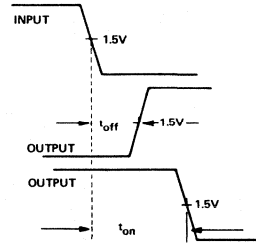
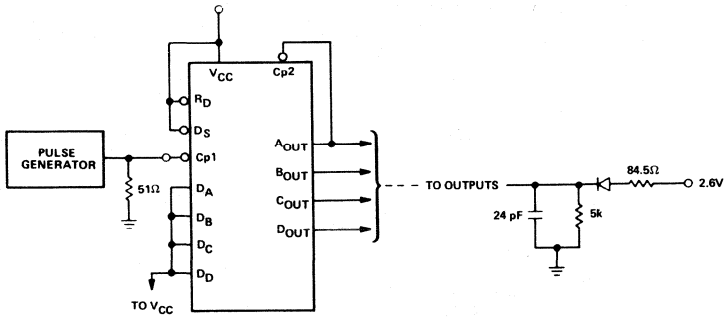


INPUT PULSE:  
 Amplitude = 3.4V  
 $t_A = 100\text{ns}$   
 $t_r = 20\text{ns}$   
 $t_B = 300\text{ns}$



AC TEST FIGURES AND WAVEFORMS (Cont'd)

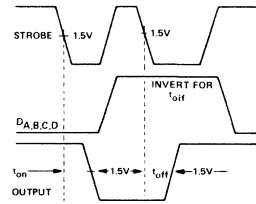
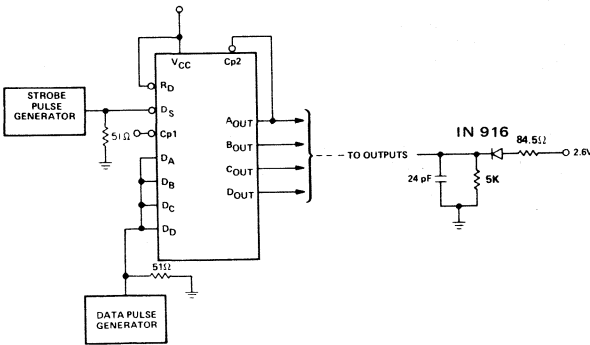
CLOCK MODE  $t_{on}/t_{off}$  DELAY



1.  $t_{on}$  and  $t_{off}$  are measured from the clock input of each binary to the Q output of that binary.
2. Each Q output will be loaded with the following load circuit:

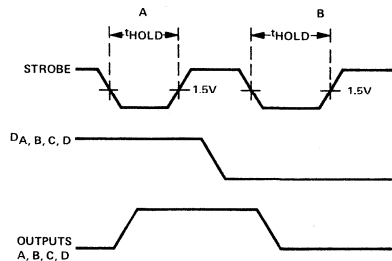
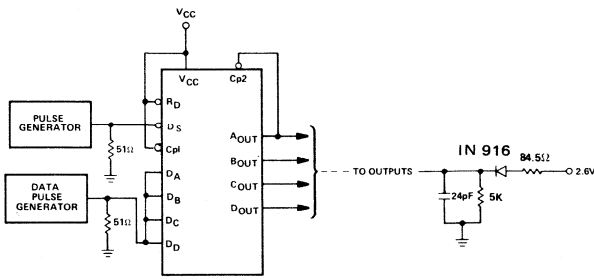
INPUT PULSE:  
Amplitude = 2.6V  
P.W. = 30ns  
 $t_r = t_f = 5ns$

DATA/STROBE  $t_{on}$   $t_{off}$



INPUT PULSE  
AMPLITUDE=2.6V  
 $t_r = t_f = 5ns$

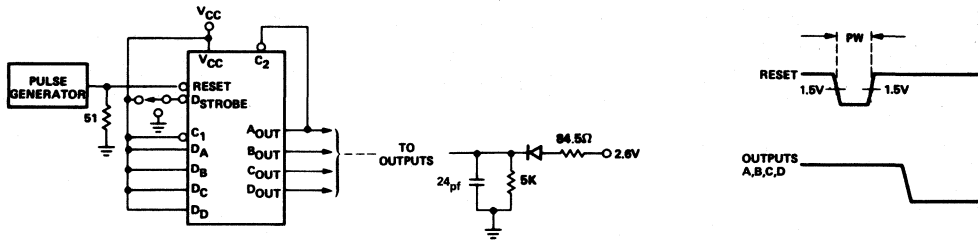
STROBE HOLD TIME



INPUT PULSE  
AMPLITUDE=2.6V  
 $t_r = t_f = 5ns$

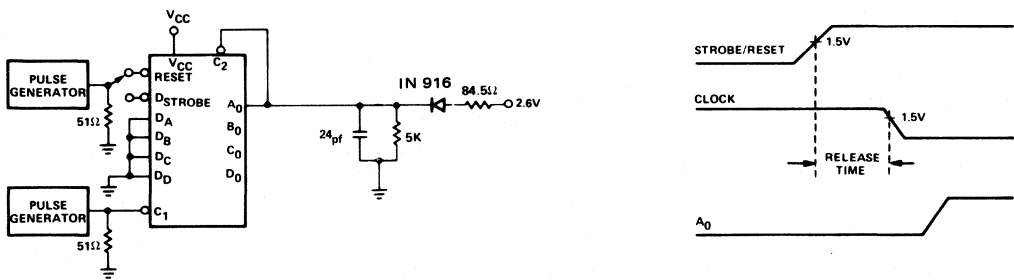
AC TEST FIGURES AND WAVEFORMS (Cont'd)

MINIMUM RESET PULSE WIDTH



INPUT PULSE:  
 Amplitude = 2.6V  
 $t_r = t_f = 5\text{ns max.}$   
 Note: Outputs must be previously brought high by placing a "0" on the D strobe input. A pulse generator may be substituted for the switch.

STROBE/RESET RELEASE TIME



Clock, Strobe/Reset Amplitude = 2.6V  
 $t_r = t_f = 5\text{ns max. PRR} = 1\text{MHz } 50\% \text{ Duty Cycle.}$

NOTES

1. All resistor values are in ohms.
2. All capacitance values are in picofarads and include jig and probe capacitance.

### DESCRIPTION

The 8290 Decade Counter and 8291 Binary Counter are high speed devices providing a wide variety of counter/storage register applications with a minimum number of packages.

The 8290 Decade Counter can be connected in the familiar BCD counting mode, in a divide-by-two and divide-by-five configuration or in the Bi-Quinary mode. The Bi-Quinary mode produces a square wave output which is particularly useful in frequency synthesizer applications.

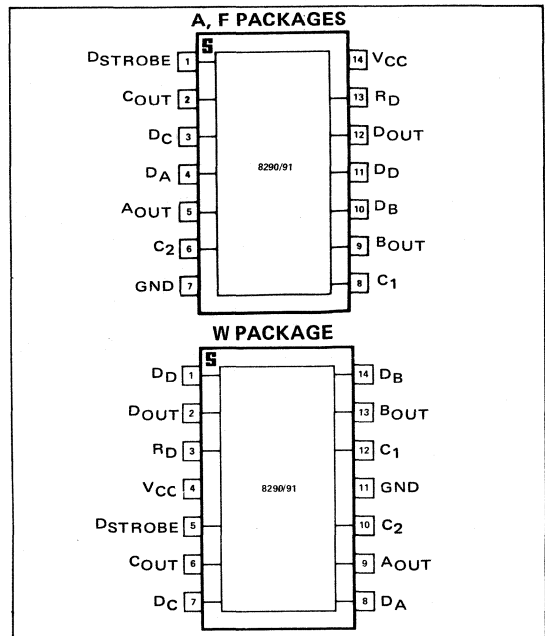
The 8291 Binary Counter may be connected as a divide-by-two, four, eight, or sixteen counter.

Both devices have strobed parallel-entry capability so that the counter may be set to any desired output state. A "1" or "0" at a data input will be transferred to the associated output when the strobe input is put at the "0" level. For additional flexibility, both units are provided with a reset input which is common to all four bits. A "0" on the reset lines produces "0" at all four outputs.

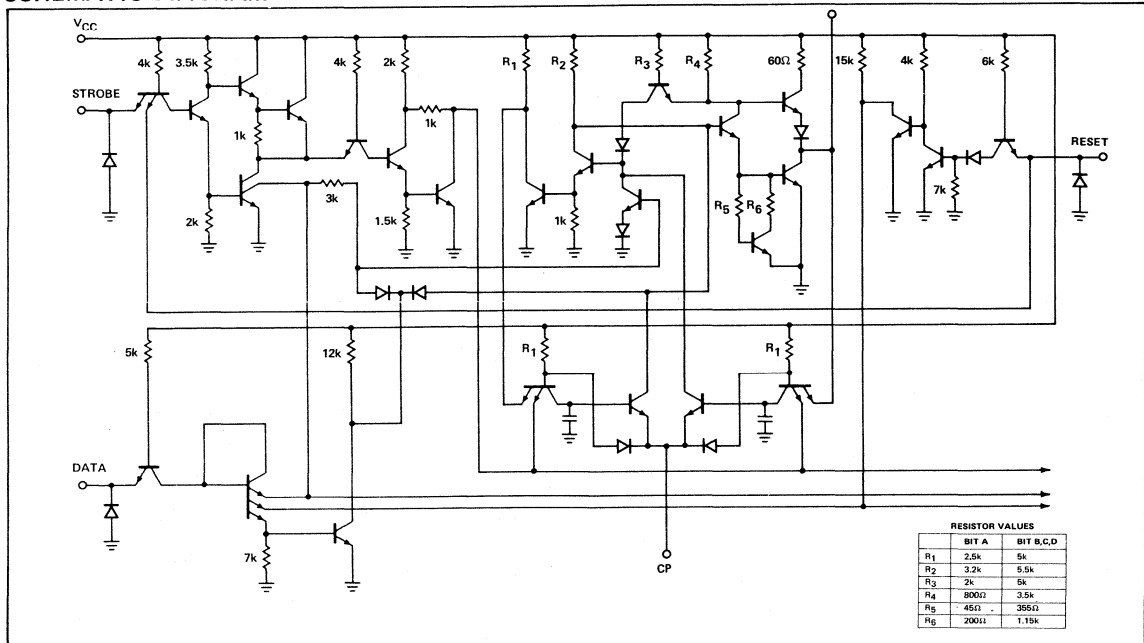
The counting operation is performed on the falling (negative going) edge of the input clock pulse.

Triggering requirements are compatible with any of the 8000 Series elements.

### PIN CONFIGURATION (Top View)



### SCHEMATIC DIAGRAM



# SIGNETICS PRESETTABLE HIGH SPEED DECADE/BINARY COUNTER ■ 8290/91

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
"1" Output Voltage	2.6	3.5		V	0.8V	2.0V	2.0V				-200 $\mu$ A	6, 7
"0" Output Voltage			0.4	V	0.8V	0.8V	0.8V				9.6mA	6, 8
"0" Input Current												
Data Strobe	-0.1		-1.6	mA	0.4		5.25V					
Data Inputs	-0.1		-1.2	mA		0.4						
Reset	-0.1		-2.8	mA	5.25V		0.4					
Clock 1	-0.1		-4.8	mA	5.25V			0.4				
Clock 2 (8290)	-0.1		-4.8	mA	5.25V				0.4			
Clock 2 (8291)	-0.1		-2.4	mA	5.25V				0.4			
"1" Input Current												
Data Strobe			40	$\mu$ A	4.5V		0.0V					
Data Inputs			40	$\mu$ A		4.5V						
Reset			80	$\mu$ A	0.0V		4.5V					
Clock 1			80	$\mu$ A	0.0V			4.5V				
Clock 2 (8290)			120	$\mu$ A	0.0V				4.5V			
Clock 2 (8291)			80	$\mu$ A	0.0V				4.5V			
Output Short Circuit Current A	-20		-70	mA							0.0V	10, 12
B, C, D	-10		-60	mA	0.0V						0.0V	10, 12
Input Voltage Rating												
Data Strobe	5.5			V	10mA							
Clock 1 & 2	5.5			V				10mA	10mA			
Data Inputs	5.5			V		10mA						
Reset	5.5			V			10mA					

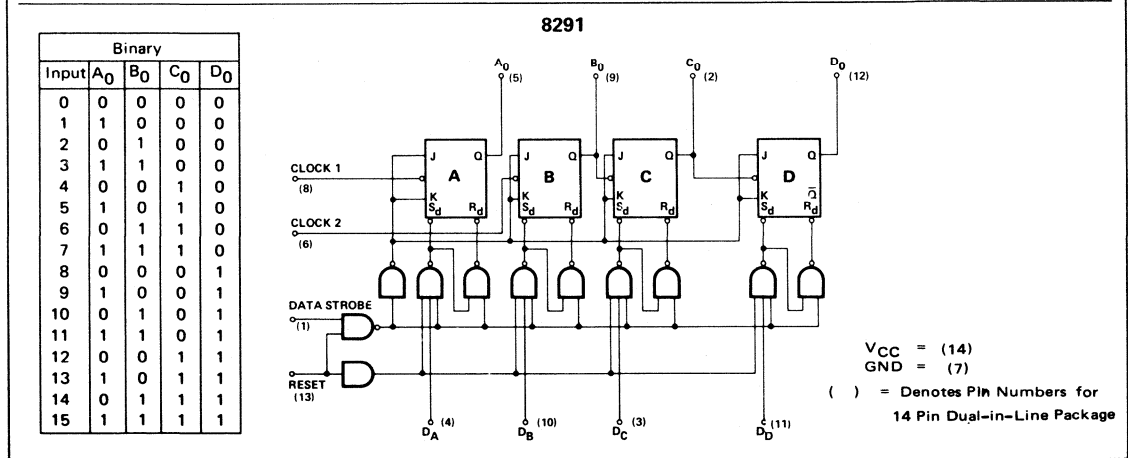
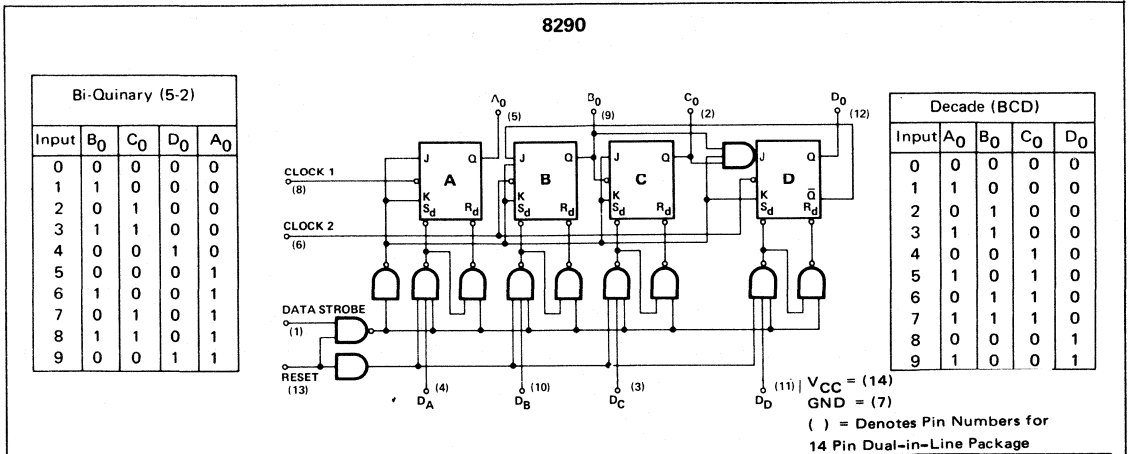
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
Power Consumption/ Supply Current		190/36.5	255/48.5	mW/ mA			0.0V	0.0V	0.0V			12
Strobe Pulse Width		15		ns						A <sub>OUT</sub>		9
Reset Pulse Width		25		ns						A <sub>OUT</sub>		9
Strobe/Reset Release Time		20		ns						A <sub>OUT</sub>		9
Clock Mode t <sub>on</sub> Delay												
Bit A		12	25	ns								9
Bits B, C, D		15	30	ns								9
Clock Mode t <sub>off</sub> Delay												
Bit A		12	23	ns								9
Bits B, C, D		15	25	ns								9
Strobed Data t <sub>on</sub> Delay (All Bits)		31	42	ns								9
Strobed Data t <sub>off</sub> Delay (All Bits)		33	42	ns								9
Toggle Rate	40	60		MHz								9
Clock Mode Switching Test			75	ns								9, 11

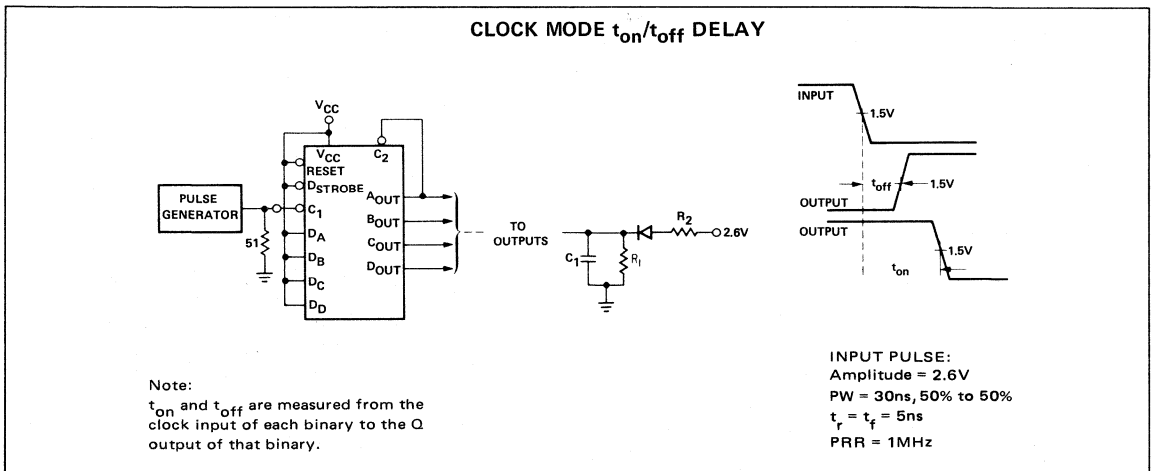
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each output and the associated data input independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ . Refer to AC Test Figures.
- Not more than one output should be shorted at a time.
- This test guarantees the device will reliably trigger on a pulse with 75ns fall-time.
- $V_{CC} = 5.25\text{V}$ .

LOGIC DIAGRAMS AND TRUTH TABLES

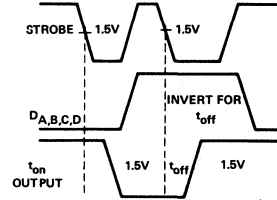
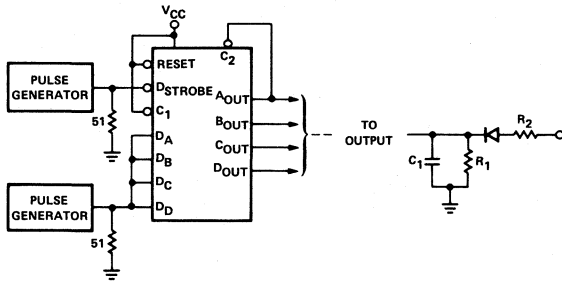


AC TEST FIGURES AND WAVEFORMS



AC TEST FIGURES AND WAVEFORMS (Cont'd)

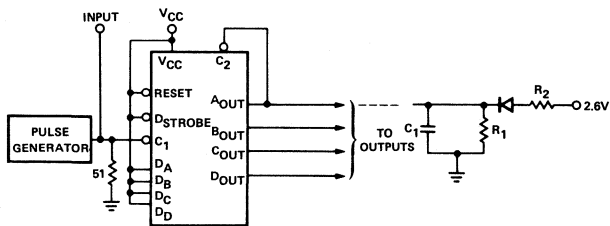
STROBED DATA  $t_{on}/t_{off}$  DELAY



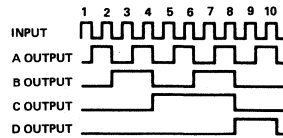
STROBE, PA = 2.6V  
 PW = 300ns, 50% to 50%  
 PRR = 1MHz  
 $t_r = t_f = 5ns$

DATA, PA = 2.6V  
 PW = 500ns, 50% to 50%  
 PRR = 500kHz  
 $t_r = t_f = 5ns$

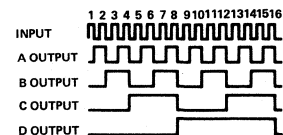
CLOCK MODE SWITCHING TEST



8290



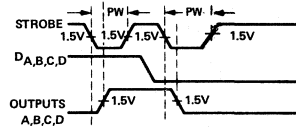
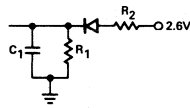
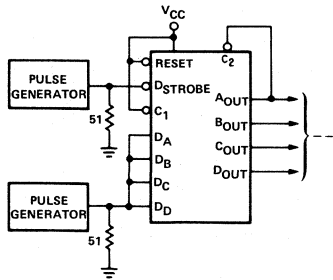
8291



INPUT PULSE:  
 Amplitude = 3.4V  
 PW = 100ns, 50% to 50%  
 PRR = 2.5MHz  
 $t_r = 20ns, t_f = 75ns$

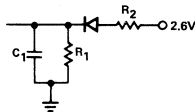
AC TEST FIGURES AND WAVEFORMS (Cont'd)

MINIMUM STROBE PULSE WIDTH



INPUT PULSE:  
Amplitude = 2.6V  
 $t_r = t_f = 5\text{ns}$

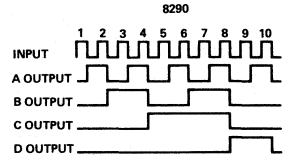
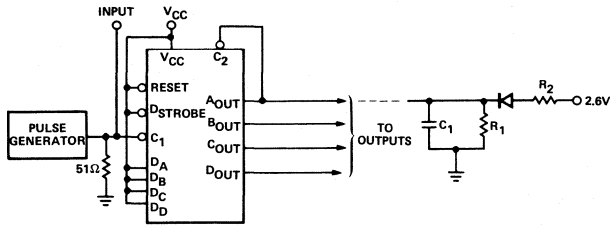
MINIMUM RESET PULSE WIDTH



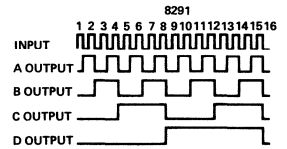
INPUT PULSE:  
Amplitude = 2.6V  
 $t_r = t_f = 5\text{ns}$   
Note: Outputs must be previously brought high by placing a "0" on the D strobe input. A pulse generator may be substituted for the switch.

AC TEST FIGURES AND WAVEFORMS (Cont'd)

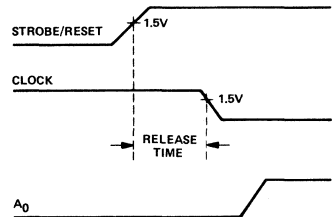
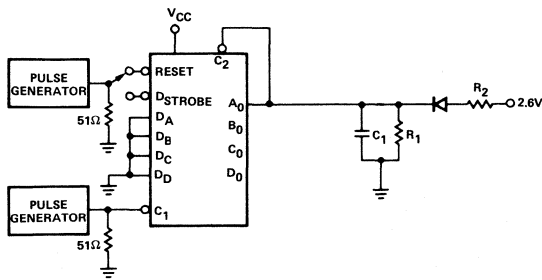
TOGGLE RATE



INPUT PULSE:  
 Amplitude = 2.6V  
 $t_r = t_f = 5\text{ ns max.}$   
 PRR = 40MHz, 50% duty cycle.



STROBE/RESET RELEASE TIME



NOTES

1. All resistor values are in ohms.
2. All capacitance values are in picofarads and include jig and probe capacitance.
3. All diodes are 1N916.
4. R1 = 20k, R2 = 146Ω, C1 = 30pF.



### DIGITAL 8000 SERIES TTL/MSI

#### DESCRIPTION

The 8292 Decade Counter and 8293 Binary Counter are low power devices providing a wide variety of counter/storage register applications with a minimum number of packages.

The 8292 Decade Counter can be connected in the familiar BCD counting mode, in a divide-by-two and divide-by-five configuration or in the Bi-Quinary mode. The Bi-Quinary mode produces a square wave output which is particularly useful in frequency synthesizer applications.

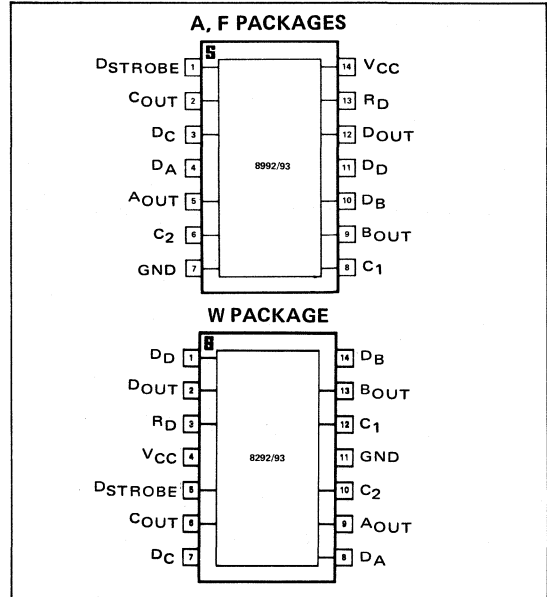
The 8293 Binary Counter may be connected as a divide-by-two, four, eight, or sixteen counter.

Both devices have strobed parallel-entry capability so that the counter may be set to any desired output state. A "1" or "0" at a data input will be transferred to the associated output when the strobe input is put at the "0" level. For additional flexibility, both units are provided with a reset input which is common to all four bits. A "0" on the reset line produces "0" at all four outputs.

The counting operation is performed on the falling (negative-going) edge of the input clock pulse.

Triggering requirements are compatible with any of the 8000 Series elements.

#### PIN CONFIGURATION (Top View)



#### ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
"1" Output Voltage	2.6	3.5		V	0.8V	2.0V	2.0V					6,8
"0" Output Voltage			0.4	V	0.8V	0.8V	0.8V					6,9
"0" Input Current												
Data Strobe	-0.1		-0.4	mA	0.4V		5.25V					
Data Inputs	-0.1		-0.4	mA		0.4V						
Reset	-0.1		-0.6	mA	5.25V		0.4V					
Clock 1	-0.1		-0.6	mA	5.25V			0.4V				
Clock 2 (8292)	-0.1		-1.2	mA	5.25V				0.4V			
Clock 2 (8293)	-0.1		-0.6	mA	5.25V				0.4V			
"1" Input Current												
Data Strobe			20	μA	4.5V		0.0V					
Data Inputs			20	μA		4.5V						
Reset			40	μA	0.0V		4.5V					
Clock 1			40	μA	0.0V			4.5V				
Clock 2 (8292)			80	μA	0.0V				4.5V			
Clock 2 (8293)			40	μA	0.0V				4.5V			
Output Short Circuit Current	-5		-45	mA	0.0V						0.0V	7, 13
Input Voltage Rating												
Data Strobe					10mA							
Clock 1 and 2	5.5			V				10mA	10mA			
Data Inputs	5.5			V		10mA						
Reset	5.5			V			10mA					

# SIGNETICS PRESETTABLE LOW POWER DECADE/BINARY COUNTER ■ 8292/93

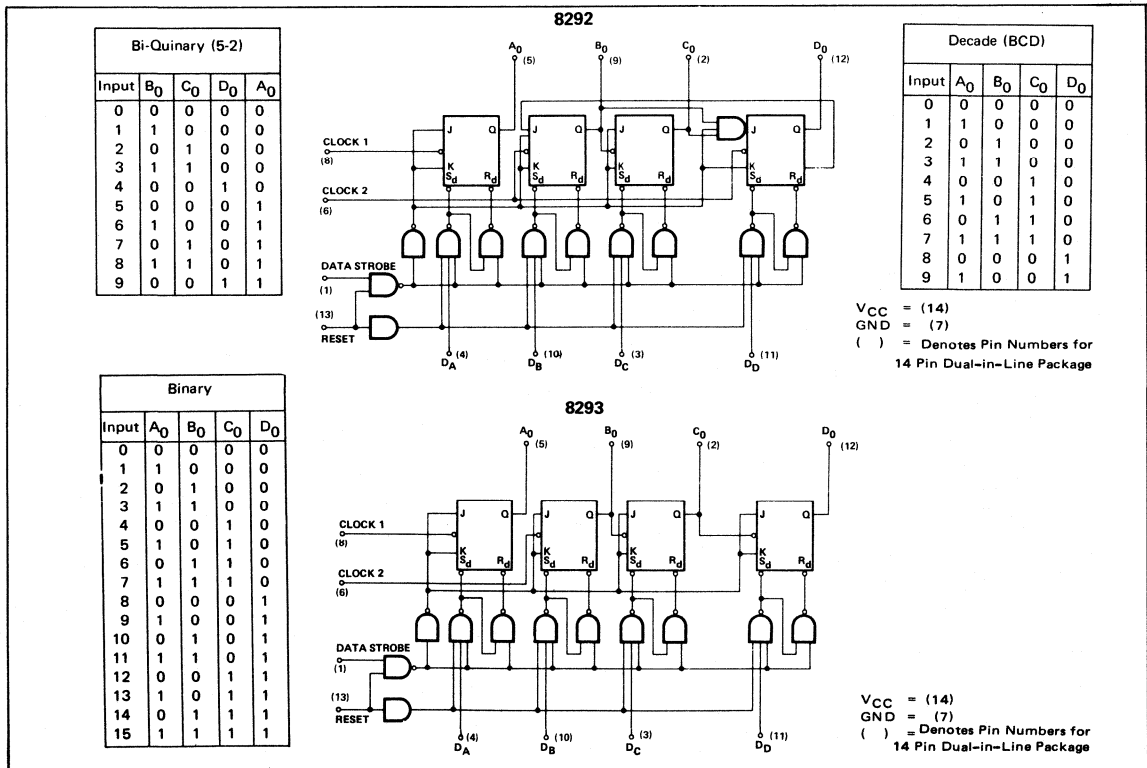
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES	
	MIN.	TYP.	MAX.	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2		OUTPUTS
Power/Current Consumption		52.5/10	69/13.1	mW/ mA			0.0V	0.0V	0.0V		13
Clock Mode $t_{on}$ Delay (All Bits)		37	55	ns							10
Clock Mode $t_{off}$ Delay (All Bits)		32	55	ns							10
Strobed Data $t_{on}$ Delay (All Bits)		80	100	ns							10
Strobed Data $t_{off}$ Delay (All Bits)		80	100	ns							10
Clock Mode Switching Test			75	ns							12
Strobe Pulse Width		60	75	ns		0.8V	2.0V	2.0V	2.0V	A <sub>OUT</sub>	
Reset Pulse Width		45	60	ns		2.0V	2.0V	2.0V	2.0V	A <sub>OUT</sub>	
Strobe/Reset Release Time			80	ns						A <sub>OUT</sub>	
Toggle Rate	5	10		MHz							

### NOTES

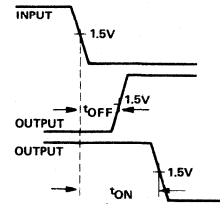
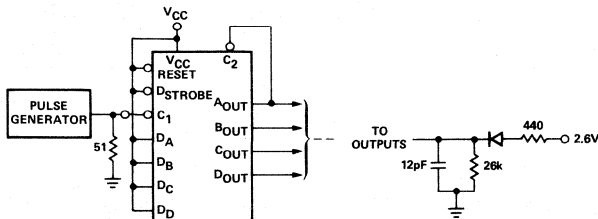
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic Definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Measurements apply to each output and the associated data input independently.
- Not more than one output should be shorted at a time.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figure.
- Manufacturer reserves the right to make design and process changes and improvements.
- This test guarantees the device will reliably trigger on a pulse with a 75ns fall-time or less.
- $V_{CC} = 5.25$  volts.

### LOGIC DIAGRAMS AND TRUTH TABLES



AC TEST FIGURES AND WAVEFORMS

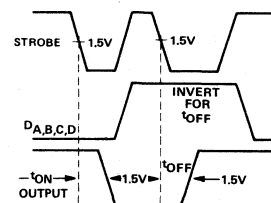
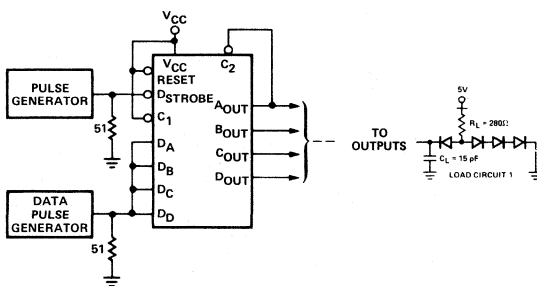
CLOCK MODE  $t_{on}/t_{off}$  DELAY



INPUT PULSE:  
 Amplitude = 2.6V  
 P.W. = 30ns, 50% to 50%  
 $t_r = t_f = 5ns$   
 PRR = 1MHz

NOTE:  
 1.  $t_{on}$  and  $t_{off}$  are measured from the clock input of each binary to the Q output of that binary.

STROBED DATA  $t_{on}/t_{off}$  DELAY

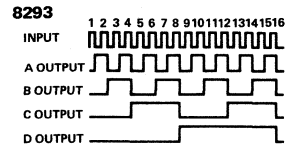
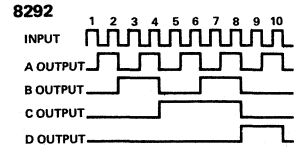
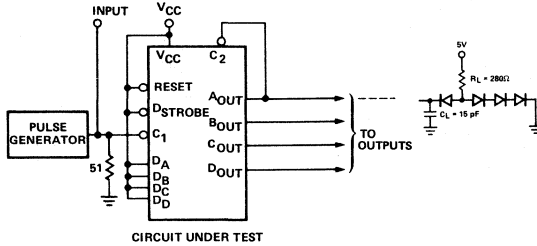


Strobe,  
 P.A. = 2.6V  
 P.W. = 300ns, 50% to 50%  
 PRR = 1MHz  
 $t_r = t_f = 5ns$

Data,  
 P.A. = 2.6V  
 P.W. = 500ns, 50% to 50%  
 PRR = 500KHz  
 $t_r = t_f = 5ns$

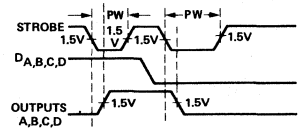
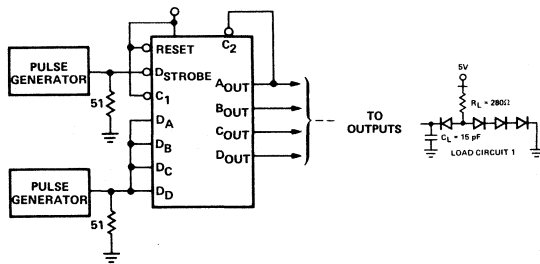
AC TEST FIGURES AND WAVEFORMS (Cont'd)

CLOCK MODE SWITCHING TEST



INPUT PULSE:  
 Amplitude = 3.4V  
 P.W. = 100ns, 50% to 50%  
 PRR = 2.5MHz  
 $t_r = 20\text{ ns}$   
 $t_f = 75\text{ ns}$

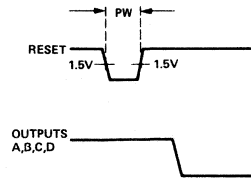
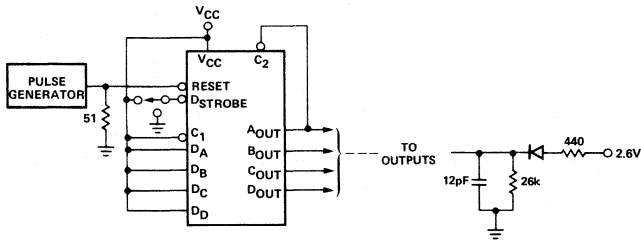
MINIMUM STROBE PULSE WIDTH



INPUT PULSE:  
 Amplitude = 2.6V  
 $t_r = t_f = 5\text{ ns max.}$

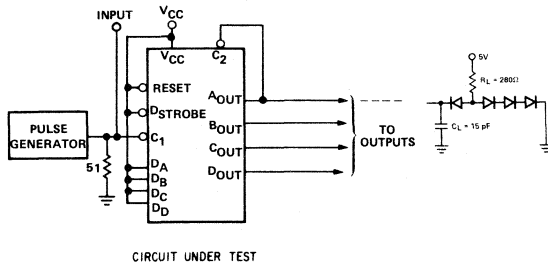
AC TEST FIGURES AND WAVEFORMS (Cont'd)

MINIMUM RESET PULSE WIDTH

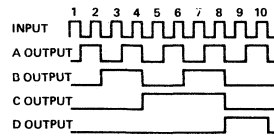


INPUT PULSE:  
Amplitude 2.6V  
 $t_r = t_f = 5\text{ns max.}$   
NOTE: Outputs must be previously brought high by placing a "Q" on the D strobe input. A pulse generator may be substituted for the switch.

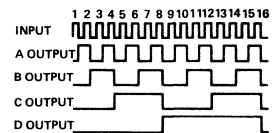
TOGGLE RATE



8292



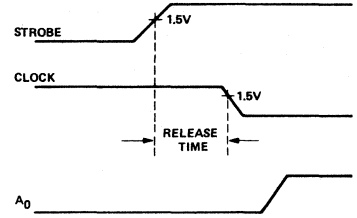
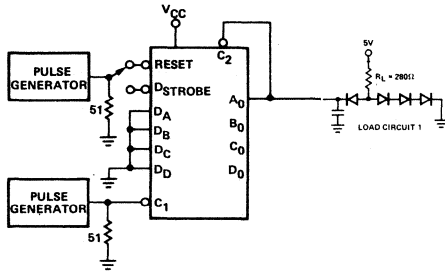
8293



INPUT PULSE:  
Amplitude = 2.6V  
PRR = 5MHz, 50% duty cycle  
 $t_r = t_f = 5\text{ns max.}$

AC TEST FIGURES AND WAVEFORMS (Cont'd)

STROBE/RESET RELEASE TIME



CLOCK, STROBE/RESET:  
 Amplitude = 2.6V  
 PRR = 1MHz, 50% duty cycle  
 $t_r = t_f = 5ns$  max.

NOTES

1. All resistor values are in ohms.
2. All capacitance values are in picofarads and include jig and probe capacitance.
3. All diodes are 1N916.

## SIGNETICS 8T SERIES INTERFACE TTL/MSI

The digital 8T Series is a standard TTL (7900 18200 series) compatible family of interface circuits that is used in such applications as line driving and receiving, tri-state busses, "party line" bus systems, driving of LED's and other dis-

plays, MOS interface, as well as in a variety of timing circuits and special purpose buffer gates. Detailed applications literature for the 8T series interface circuits is published in the Signetics Applications Handbook.

## SIGNETICS 8T SERIES INTERFACE APPLICATIONS NOTES

8T04/5/6	BCD to Seven Segment Decoder/Drivers
8T09	Quad Tri-State Bus Driver
8T10	Quad Tri-State Bus Latch
8T13	Dual High Current Line Driver
8T14	Triple Line Receiver with Hysteresis
8T14	Schmitt Trigger Applications
8T15	Dual Communications Line Driver EIA Standard RS232-C Mil Std 188-B
8T16	Dual Communications Line Receiver EIA Standard RS232-C Mil Std 188-C
8T18	High Voltage to TTL Interface Gate
8T20	Bi-Directional One-Shot
8T22/9601	Retriggerable Monostable Multivibrator (One-Shot)
8T23	Dual IBM System/360 and System/370 I/O Interface Line Driver
8T24	Triple IBM System/360 and System/370 I/O Interface Line Receiver
8T25	Dual MOS Sense Amplifier/Latch
8T26	Quad Tri-State Bus Transceiver
8T80/90	Open Collector Gates/Buffers (TTL to High Voltage)
8T363	Dual Zero-Crossing Detector
8T380	Quad Bus Receiver/Schmitt Trigger

### DIGITAL 8T SERIES INTERFACE TTL/MSI

#### DESCRIPTION

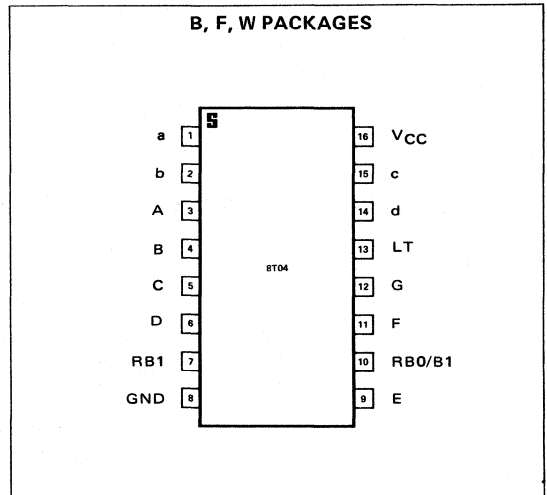
The 8T04 consists of the necessary logic to decode a 4-bit BCD code to seven segment (0 through 9) readout, as well as some selected signs and letters.

Incorporated in this device is a blanking circuit which turns all segments off when activated. The blanking circuit allows suppression of all numerically insignificant zeros, thereby presenting an easily read display.

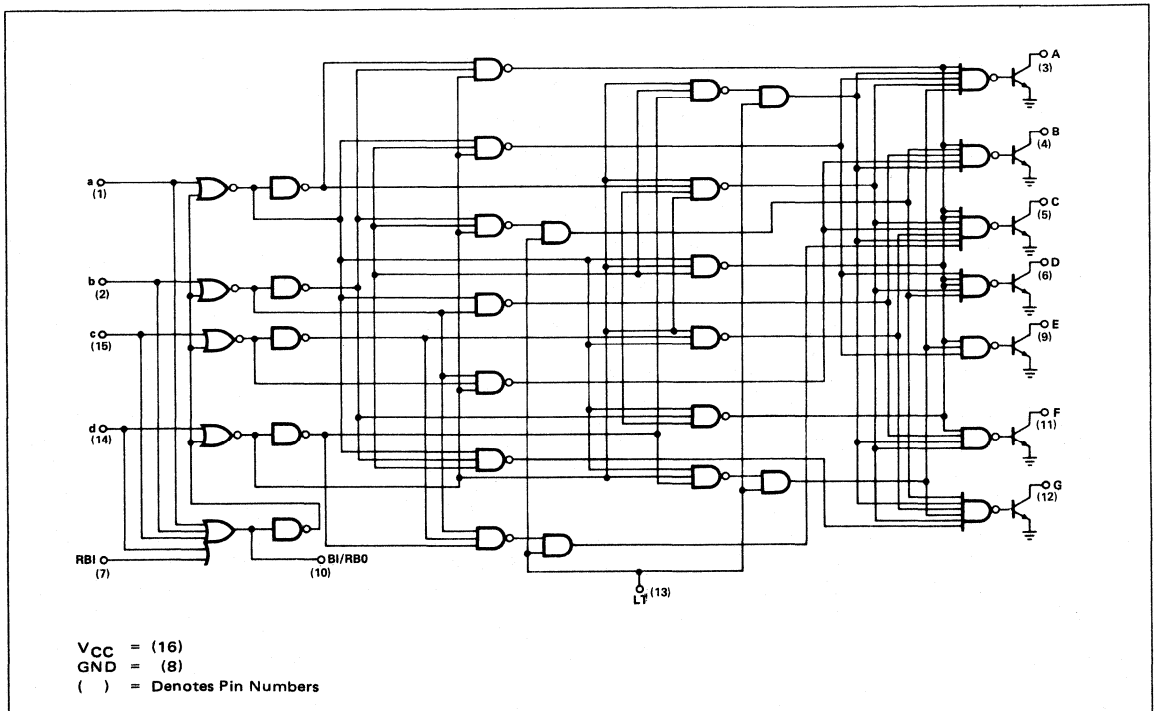
Also included is the necessary circuitry to implement suppression of leading and/or trailing zeros. A Lamp Test control is provided to turn all segments on. The Lamp Test allows the viewer to check the validity of the display lamps.

High performance bare collector output transistors are used in the 8T04 for directly driving incandescent lamps or common anode LED displays.

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM





# SIGNETICS SEVEN SEGMENT DECODER/DRIVER ■ 8T04

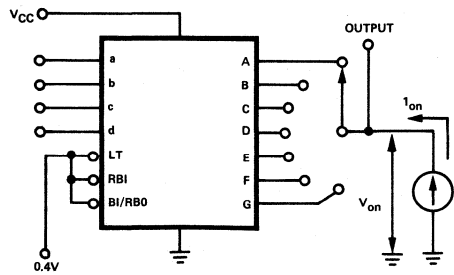
## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	LT	RB1	RBO BI	DRIVEN INPUTS	OUTPUTS	
"1" Output Voltage RBO	3.1			V			-160μA			7, 9
"0" Output Voltage RBO			0.4	V		0.8V	4.8mA	0.8V		8, 9
A-G			0.50	V	0.4V	0.4V	0.4V		40mA	8, 9
"1" Output Leakage Current (A-G)			100	μA		0.8V			6.0V	9, 10
"1" Input Current RBI			40	μA		4.5V				
LT			160	μA	4.5V					
All Other Inputs			80	μA		4.5V	4.5V	4.5V		
"0" Input Current RBI						0.4V				
BI	-1		-1.2	mA			0.4V			
LT	-1		-2.2	mA	0.4V					
All Other Inputs	-1		-10	mA	0.4V					
Input Voltage Rating	5.5			V			10mA			11
Power/Current Consumption: "S" Temperature Range			394/75	mW/mA						11
"N" Temperature Range			446/85	mW/mA						11

**NOTES**

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current is defined as into the terminal referenced.
4. Positive NAND Logic Definition:  
"UP" Level = "1", "DOWN" = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Measurements apply to each gate element independently.
7. Output source current is supplied through a resistor to ground.
8. Output sink current is supplied through a resistor to V<sub>CC</sub>.
9. See truth table: "1" Threshold = 2.0V for a,b,c,d.  
"0" Threshold = 0.8V for a,b,c,d.
10. Connect an external 1k ±1% resistor to the output for this test.
11. V<sub>CC</sub> = 5.25V.

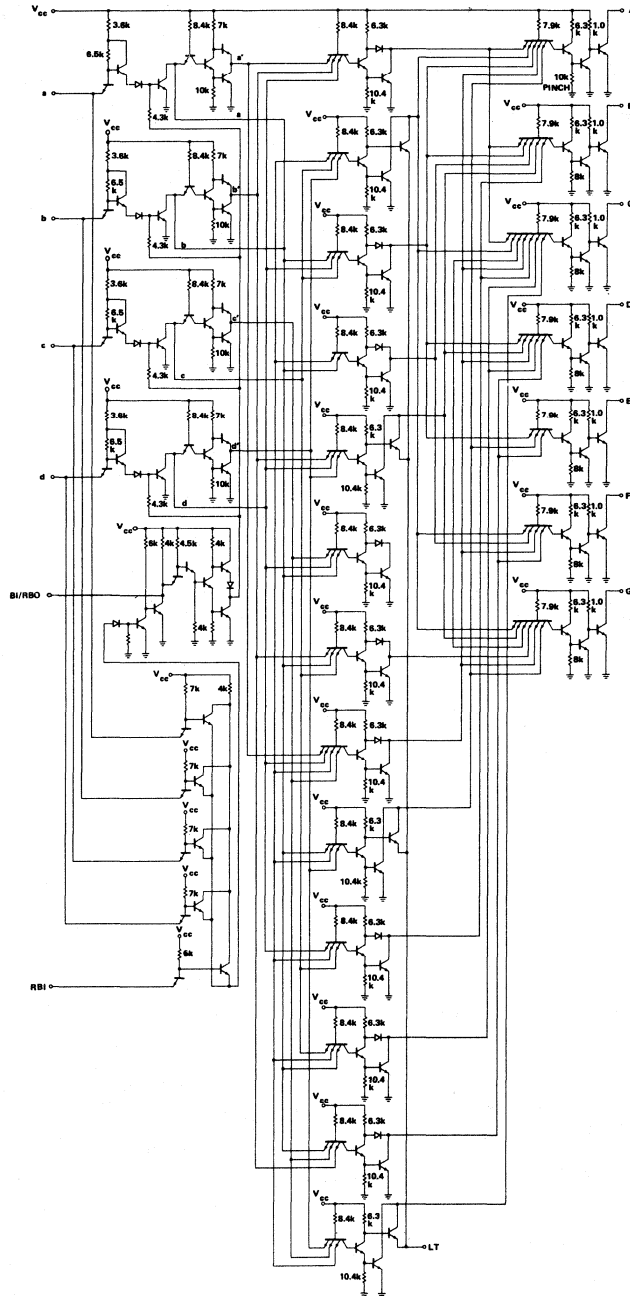
### TEST FIGURE FOR "0" OUTPUT VOLTAGE



Each output is tested separately in the ON state.

# SIGNETICS SEVEN SEGMENT DECODER/DRIVER ■ 8T04

## SCHEMATIC DIAGRAM



TRUTH TABLE

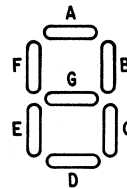
INPUTS						BI/RBO	OUTPUTS							
INPUT CODE				LAMP TEST	RBI		NOTE	OUTPUT STATE						
d	c	b	a	LT				A	B	C	D	E	F	G
X	X	X	X	0	X	X	0	0	0	0	0	0	0	8
X	X	X	X	1	X	0	1	1	1	1	1	1	1	BLK
0	0	0	0	1	0	(Note 1 & 2) 0	1	1	1	1	1	1	1	BLK
0	0	0	0	1	1	(Note 2) 1	0	0	0	0	0	0	1	0
0	0	0	1	1	X	1	1	0	0	1	1	1	1	1
0	0	1	0	1	X	1	0	0	1	0	0	1	0	2
0	0	1	1	1	X	1	0	0	0	0	1	1	0	3
0	1	0	0	1	X	1	1	0	0	1	1	0	0	4
0	1	0	1	1	X	1	0	1	0	0	1	0	0	5
0	1	1	0	1	X	1	1	1	0	0	0	0	0	6
0	1	1	1	1	X	1	0	0	0	1	1	1	1	7
1	0	0	0	1	X	1	0	0	0	0	0	0	0	8
1	0	0	1	1	X	1	0	0	0	1	1	0	0	9
1	0	1	0	1	X	1	1	1	1	1	1	1	0	BLK
1	0	1	1	1	X	1	1	1	1	1	1	1	1	BLK
1	1	0	0	1	X	1	0	0	0	1	0	0	0	BLK
1	1	0	1	1	X	1	1	1	0	1	1	1	1	BLK
1	1	1	0	1	X	1	1	1	1	0	0	0	1	BLK
1	1	1	1	1	X	1	1	1	1	1	1	1	1	BLK

\*COMMA

X = Don't care, either "1" or "0".  
BI/RBO is an internally wired OR output.

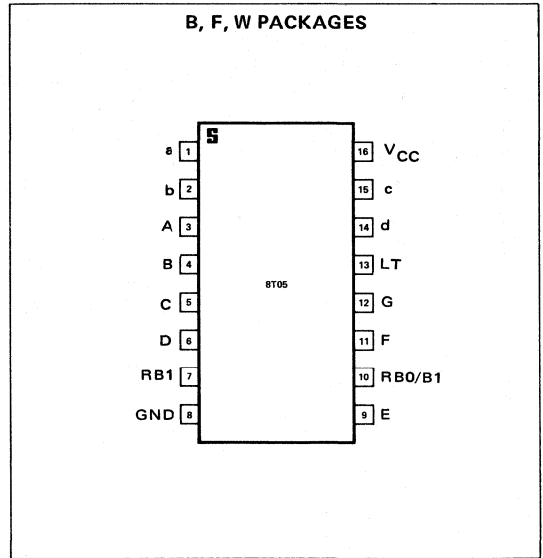
NOTE:

1. BI/RBO used as input.
2. BI/RBO should not be forced high when a,b,c,d, RBI terminals are low, or damage may occur to the unit.



DIGITAL 8T SERIES INTERFACE TTL/MSI

### PIN CONFIGURATION (Top View)



The 8T05 consists of the necessary logic to decode a 4-Bit BCD code to seven segment (0 through 9) readout as well as some selected signs and letters.

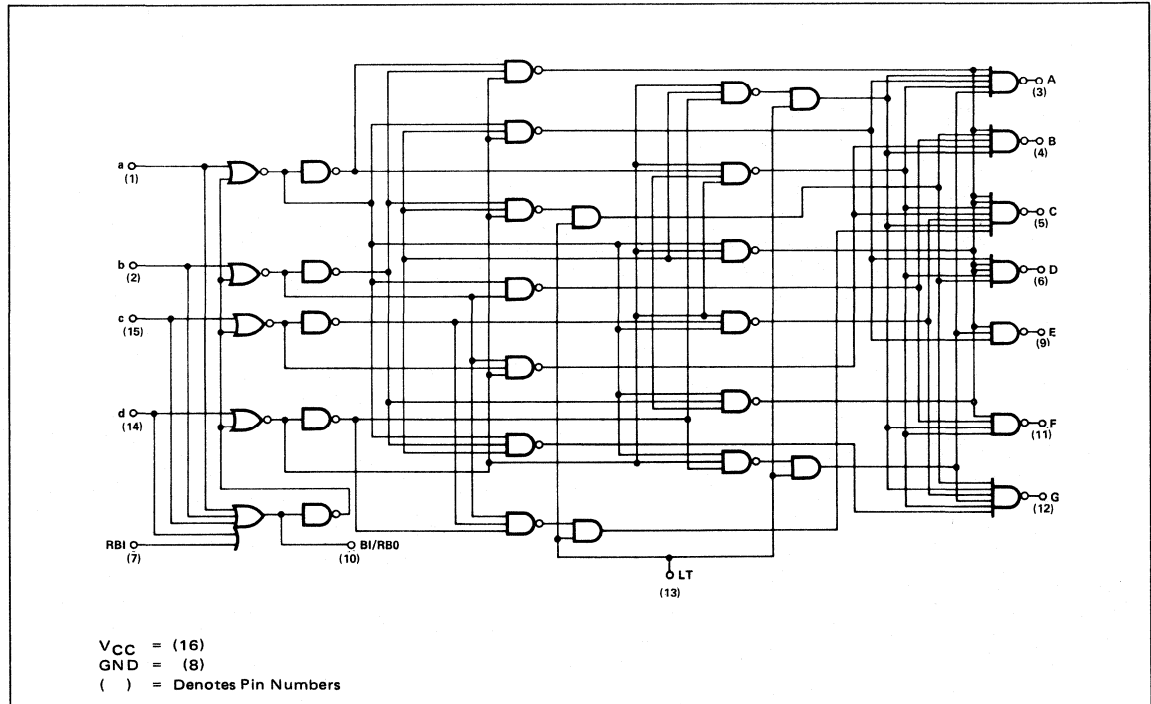
A Ripple Blanking input is provided to implement suppression of leading and/or trailing zeros. The suppression of all numerically insignificant zeros provides an easily read display.

Incorporated in the Ripple Blanking output (BI/RBO) is the facility to ground all the outputs. Blanking of the outputs allows for intensity modulation.

A Lamp Test input is provided which, when grounded forces all segment outputs high. This allows the viewer to check the validity of the display presentation by testing the integrity of the lamps.

The 8T05 has resistor pullups on the outputs to provide source current sufficient to drive interfacing elements. This allows the unit to drive high voltage transistors for neon displays. The 8T05 can also be used to drive common cathode LED displays without the need for external resistors.

### LOGIC DIAGRAM



# SIGNETICS SEVEN SEGMENT DECODER/TRANSISTOR DRIVER ■ 8T05

## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

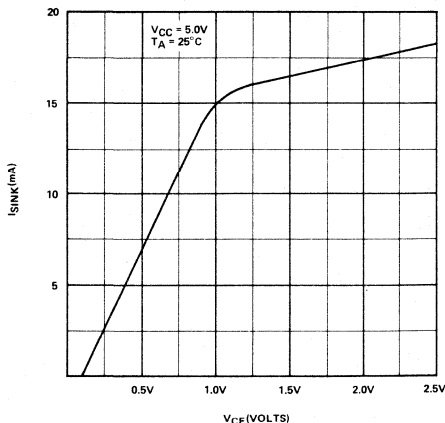
CHARACTERISTICS	LIMITS				LT	TEST CONDITIONS			OUTPUTS	NOTES
	MIN	TYP	MAX	UNITS		RBI	RBO BI	DRIVEN INPUTS		
A-G "1" Output Voltage	3.9			V	0.4V				-500 $\mu$ A	7, 9
A-G Output Source Current	-2.3			mA	0.4V				1.0V	
A-G "0" Output Voltage			0.3	V	4.5V	0.4V	0.4V		+500 $\mu$ A	8, 9
RBO "1" Output Voltage	3.1			V			-160 $\mu$ A			7, 9
RBO "0" Output Voltage			0.4	V		0.8V	4.8mA	0.8V		8, 9
"1" Input Current										
RBI			40	$\mu$ A		4.5V				
LT			160	$\mu$ A	4.5V					
All other Inputs			80	$\mu$ A		4.5V	4.5V	4.5V		
"0" Input Current										
RBI	-1		-1.2	mA		0.4V				
BI	-1		-2.2	mA			0.4V			
LT	-1		-1.0	mA	0.4V					
All Other Inputs	-1		-1.6	mA				0.4V		
Input Voltage Rating	5.5			V				10mA		
Power/Current Consumption:										
"S" Temperature Range			394/75	mW/mA						10
"N" Temperature Range			110/85	mW/mA						10

### NOTES

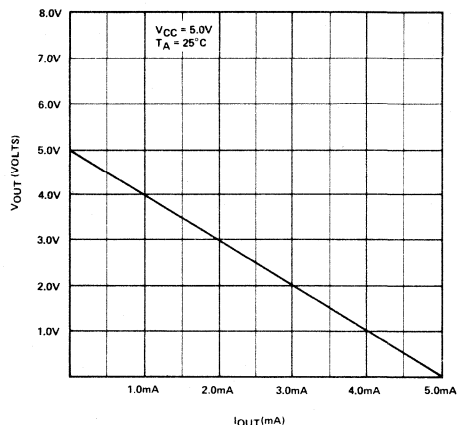
1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current is defined as into the terminal referenced.
4. Positive NAND Logic Definition:  
"UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Measurements apply to each element independently.
7. Output source current is supplied through a resistor to ground.
8. Output sink current is supplied through a resistor to  $V_{CC}$ .
9. See truth table: "1" Threshold = 2.0V for a,b,c,d.  
"0" Threshold = 0.8V for a,b,c,d.
10.  $V_{CC} = 5.25V$ .

## TYPICAL CHARACTERISTIC CURVES

**TYPICAL CURRENT SINK CAPABILITY VERSUS  $V_{CE}(SAT)$  (OUTPUTS A-G)**

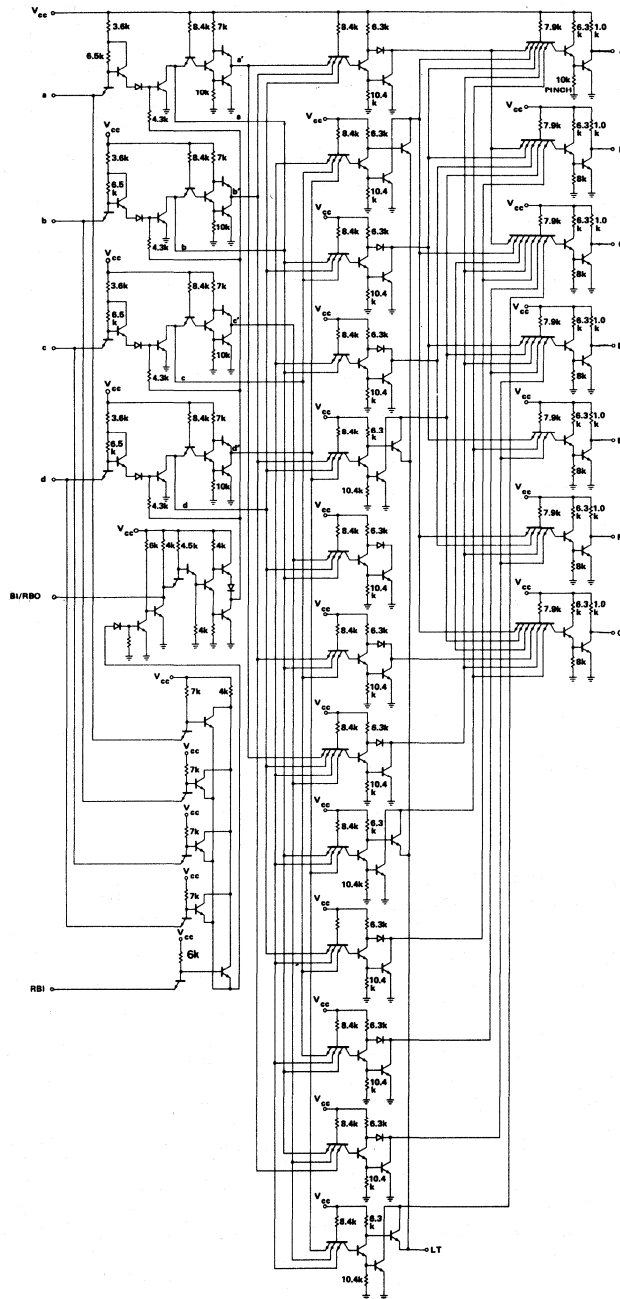


**TYPICAL OUTPUT CURRENT VERSUS OUTPUT VOLTAGE (OUTPUTS A-G)**



# SIGNETICS SEVEN SEGMENT DECODER/TRANSISTOR DRIVER ■ 8T05

## SCHEMATIC DIAGRAM



TRUTH TABLE

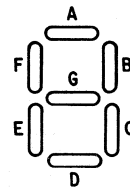
INPUTS				BI/RBO	OUTPUTS									
INPUT CODE		LAMP TEST	RBI		OUTPUT STATE							DISPLAY CHARACTER		
d	c	b	a	LT		Note	A	B	C	D	E	F	G	
X	X	X	X	0	X	X	1	1	1	1	1	1	1	8
X	X	X	X	1	X	0	0	0	0	0	0	0	0	BLK
0	0	0	0	1	0	(Note 1 & 2) 0	0	0	0	0	0	0	0	BLK
0	0	0	0	1	1	(Note 2) 1	1	1	1	1	1	1	0	0
0	0	0	1	1	X	1	0	1	1	0	0	0	0	1
0	0	1	0	1	X	1	1	1	0	1	1	0	1	2
0	0	1	1	1	X	1	1	1	1	1	0	0	1	3
0	1	0	0	1	X	1	0	1	1	0	0	1	1	4
0	1	0	1	1	X	1	1	0	1	1	0	1	1	5
0	1	1	0	1	X	1	0	0	1	1	1	1	1	6
0	1	1	1	1	X	1	1	1	1	0	0	0	0	7
1	0	0	0	1	X	1	1	1	1	1	1	1	1	8
1	0	0	1	1	X	1	1	1	1	0	0	1	1	9
1	0	1	0	1	X	1	0	0	0	0	0	0	1	1
1	0	1	1	1	X	1	0	0	0	0	0	0	0	BLK
1	1	0	0	1	X	1	1	1	1	0	1	1	1	8
1	1	0	1	1	X	1	0	0	1	0	0	0	0	1
1	1	1	0	1	X	1	0	0	0	1	1	1	0	L
1	1	1	1	1	X	1	0	0	0	0	0	0	0	BLK

\*COMMA

X = Don't care, either "1" or "0".  
BI/RBO is an internally wired OR output.

NOTE:

1. BI/RBO used as input.
2. BI/RBO should not be forced high when a, b, c, d, RBI terminals are low, or damage may occur to the unit.

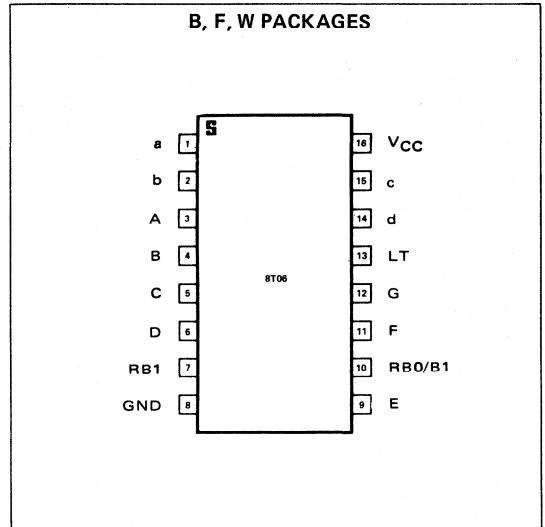


### DIGITAL 8T SERIES INTERFACE TTL/MSI

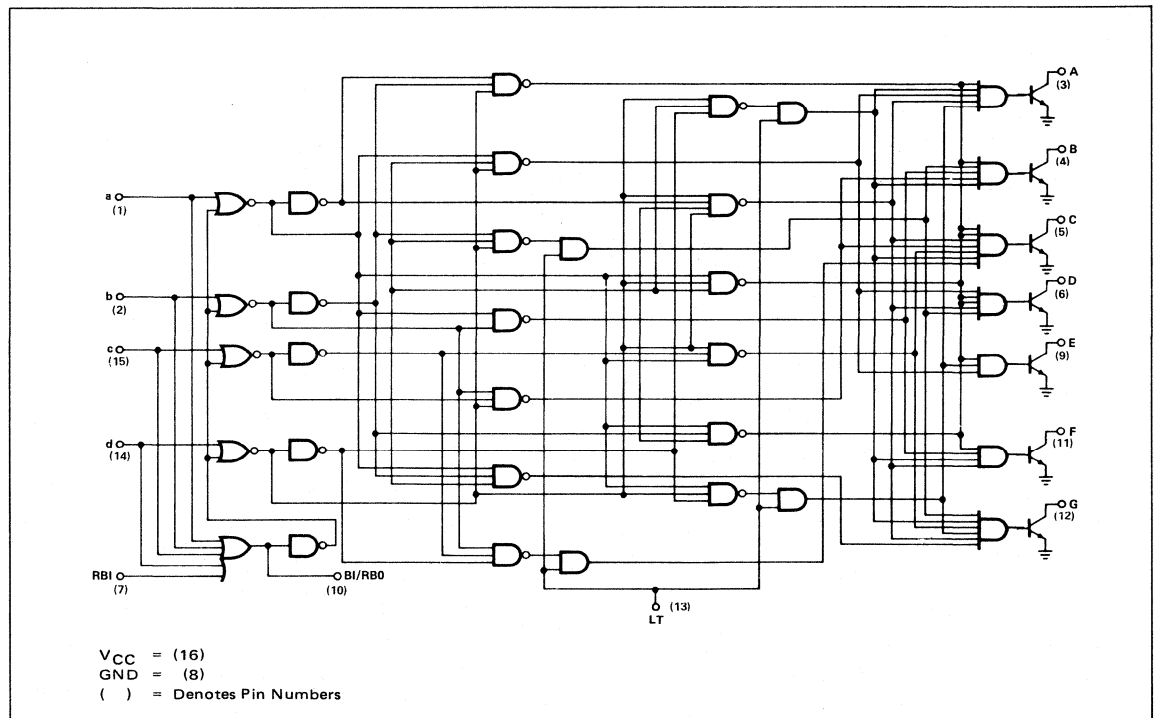
#### DESCRIPTION

The 8T06 is a monolithic MSI circuit consisting of the necessary logic to decode a 4-bit BCD code to drive 7-segment indicators directly. Open-collector outputs are used for high current source applications, such as driving common cathode LED displays and discrete active components. The 8T06 seven segment decoder/driver accepts a 4-bit binary code and decodes all possible inputs as decimals 0-9 or selected signs and letters. Auxiliary inputs are provided for maximum versatility. The ripple blanking inputs (RBI) and the ripple blanking output (RBO) may be used for automatic leading and/or trailing-edge zero suppression. The RBO output also acts as an overriding blanking input (BI) which may be used for intensity modulation or strobing of the display. A lamp test (LT) input is provided to check the integrity of the display by activating all outputs independent of the input code.

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM



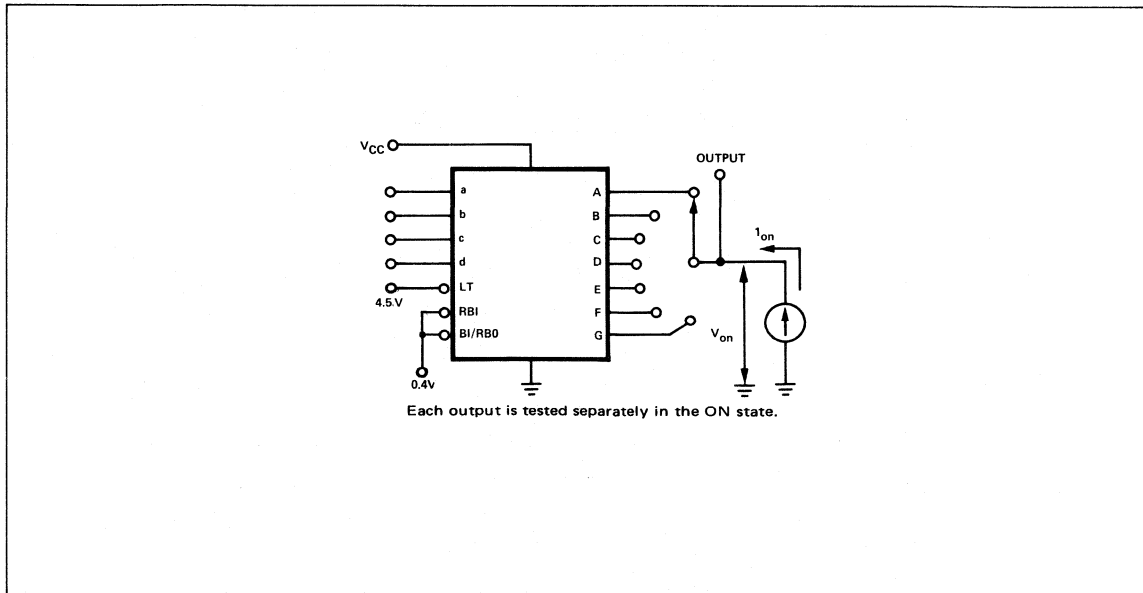


ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	LT	RB1	RB0 B1	DRIVEN INPUTS	OUTPUTS	
"1" Output Voltage RBO	3.1			V			-160 $\mu$ A			7, 9
"0" Output Voltage (A-G) RBO			0.5 0.4	V V	4.5V	0.4V 0.8V	0.4V 4.8mA	0.8V	40mA	8, 9 8, 9
"1" Output Leakage Current (A-G)			100	$\mu$ A	0.4V				6.0V	9, 10
"1" Input Current RBI			40	$\mu$ A		4.5V				
LT			160	$\mu$ A	4.5V					
All Other Inputs			80	$\mu$ A		4.5V	4.5V	4.5V		
"0" Input Current RBI	-1		-1.2	mA		0.4V				
BI	-1		-2.2	mA			0.4V			
LT	-1		-10	mA	0.4V					
All Other Inputs	-1		-1.6	mA	0.4V	0.4V	0.4V	0.4V		
Input Voltage Rating	5.5			V		10mA		10mA		
Power/Current Consumption: "S" Temperature Range			394/75	mW/mA						11
"N" Temperature Range			446/85	mW/mA						11

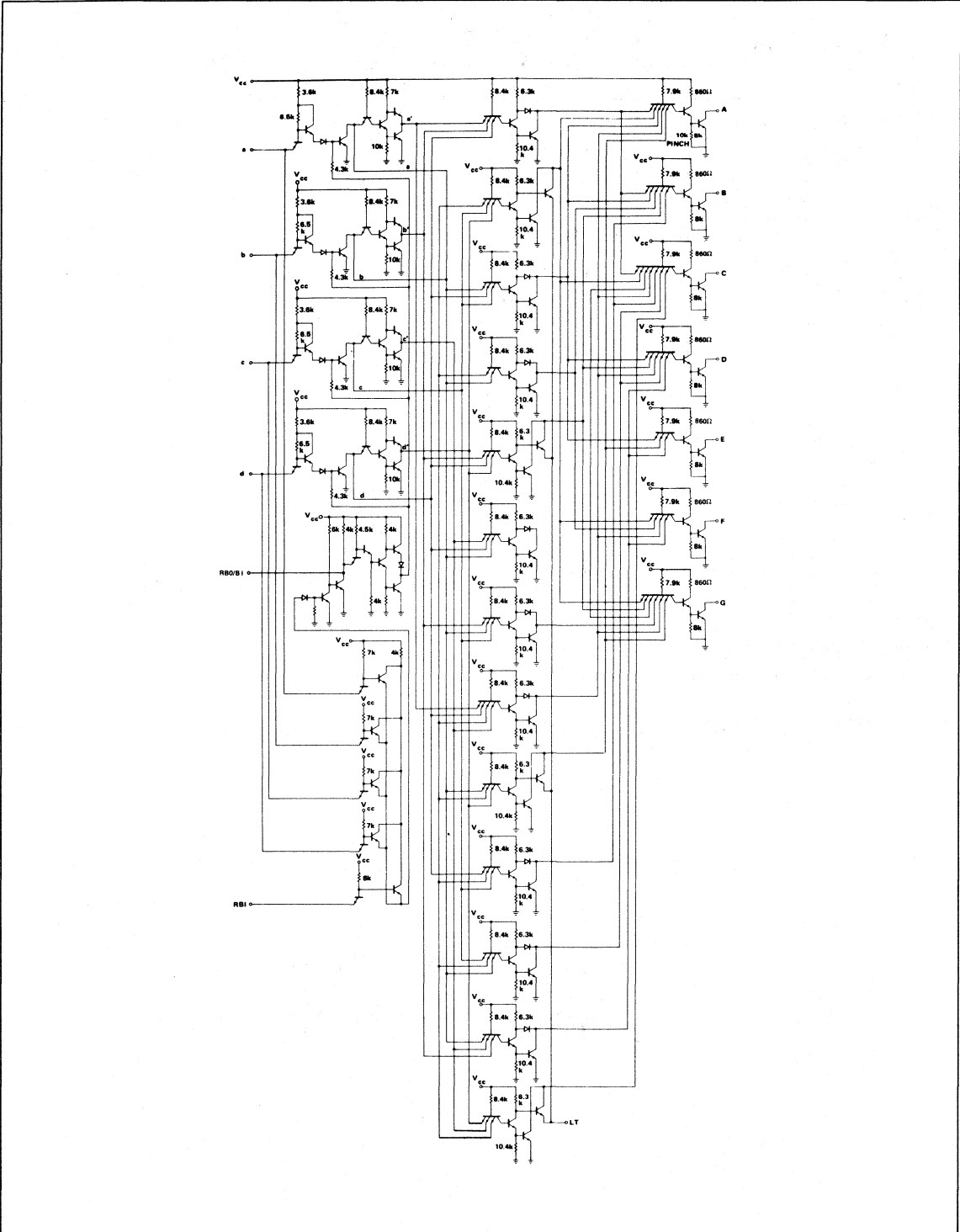
- NOTES
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
  - All measurements are taken with ground pin tied to zero volts.
  - Positive current is defined as into the terminal referenced.
  - Positive NAND Logic Definitions:  
"UP" Level = "1", "DOWN" Level = "0".
  - Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
  - Measurements apply to each gate element independently.
  - Output source current is supplied through a resistor to ground.
  - Output sink current is supplied through a resistor to  $V_{CC}$ .
  - See truth table: "1" Threshold = 2.0V for a,b,c,d.  
"0" Threshold = 0.8V for a,b,c,d.
  - Connect an external 1k  $\pm$ 1% resistor to the output for this test.
  - $V_{CC}$  = 5.25V.

TEST FIGURE FOR "0" OUTPUT VOLTAGE



SIGNETICS SEVEN SEGMENT DECODER/DISPLAY DRIVER ■ 8T06

SCHEMATIC DIAGRAM



TRUTH TABLE

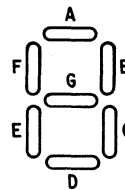
INPUTS				LAMP TEST	RBI	BI/RBO	OUTPUTS							DISPLAY CHARACTER
INPUT CODE							OUTPUT STATE							
d	c	b	a	LT		Note	A	B	C	D	E	F	G	
X	X	X	X	0	X	X	1	1	1	1	1	1	1	8
X	X	X	X	1	X	0	0	0	0	0	0	0	0	BLK
0	0	0	0	1	0	(Note 1 & 2) 0	0	0	0	0	0	0	0	BLK
0	0	0	0	1	1	(Note 2) 1	1	1	1	1	1	1	0	0
0	0	0	1	1	X	1	0	1	1	0	0	0	0	:
0	0	1	0	1	X	1	1	1	0	1	1	0	1	2
0	0	1	1	1	X	1	1	1	1	1	0	0	1	3
0	1	0	0	1	X	1	0	1	1	0	0	1	1	4
0	1	0	1	1	X	1	1	0	1	1	0	1	1	5
0	1	1	0	1	X	1	0	0	1	1	1	1	1	6
0	1	1	1	1	X	1	1	1	1	0	0	0	0	7
1	0	0	0	1	X	1	1	1	1	1	1	1	1	8
1	0	0	1	1	X	1	1	1	1	0	0	1	1	9
1	0	1	0	1	X	1	0	0	0	0	0	0	0	BLK
1	0	1	1	1	X	1	0	0	0	0	0	0	0	BLK
1	1	0	0	1	X	1	1	1	1	0	1	1	1	0
1	1	0	1	1	X	1	0	0	1	0	0	0	0	.
1	1	1	0	1	X	1	0	0	0	1	1	1	0	1
1	1	1	1	1	X	1	0	0	0	0	0	0	0	BLK

\*COMMA

X = Don't care, either "1" or "0".  
BI/RBO is an internally wired OR output.

NOTE:

1. BI/RBO used as input.
2. BI/RBO should not be forced high when a, b, c, d, RBI terminals are low, or damage may occur to the unit.



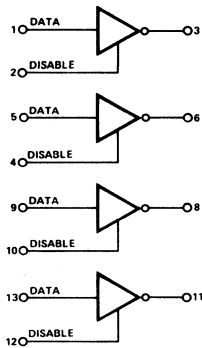
### DIGITAL 8T SERIES INTERFACE TTL/MSI

#### DESCRIPTION

The 8T09 is a high speed quad bus driver device for applications requiring up to 25 loads interconnected on a single bus.

The tri-state outputs present a high impedance to the bus when disabled, (control input "1") and active drive when enabled (control input "0"). This eliminates the resistor pull-up requirement while providing performance superior to open collector schemes. Each output can sink 40mA and drive 300pF loading with guaranteed propagation delay less than 20 nanoseconds.

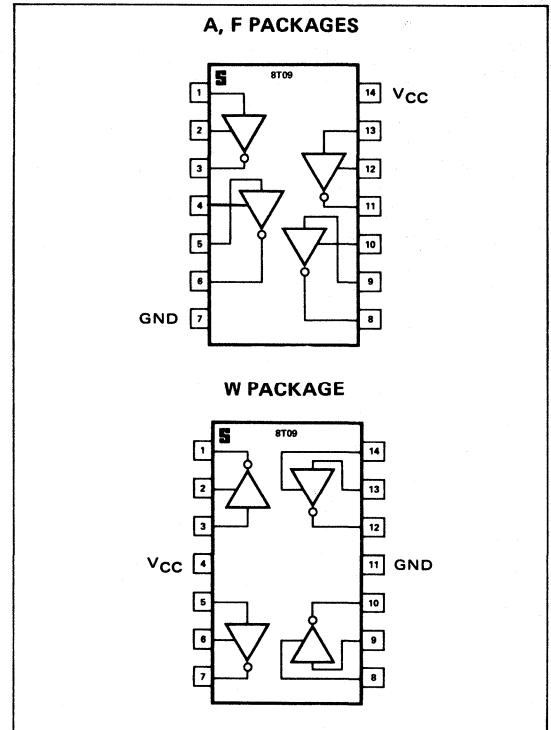
#### LOGIC DIAGRAM AND TRUTH TABLE



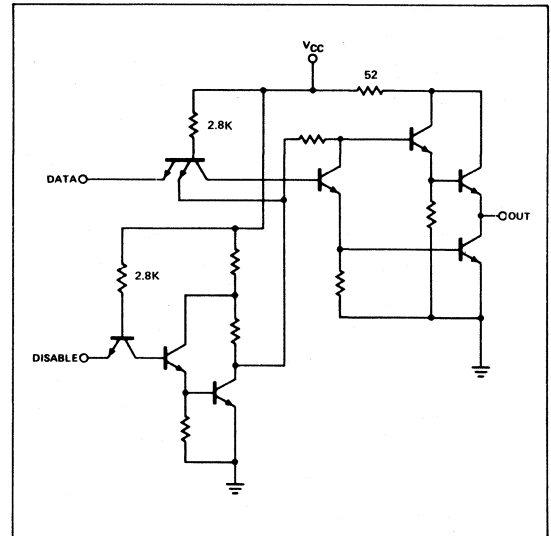
Data	Disable	Output
0	0	1
1	0	0
0	1	Hi-Z
1	1	Hi-Z

$V_{CC}$  = (14)  
 $GND$  = (7)  
 ( ) = Denotes Pin Numbers for  
 14 Pin Dual-in-Line Package

#### PIN CONFIGURATIONS (Top View)



#### SCHEMATIC DIAGRAM



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	DATA	DISABLE	OUTPUTS	
"1" Output Voltage	2.4	3.0		V	0.8V	0.8V	-5.2mA	7
"0" Output Voltage		0.2	0.4	V	2.0V	0.8V	40mA	8
Output Leakage Current	-40		+40	$\mu$ A		2.0V	0.4V or 2.4V	3
"1" Input Current			40	$\mu$ A		4.5V		
"0" Input Current			-2.0	mA	0.4V	0.4V		
Input Voltage Rating	5.5			V	10mA	10mA		
Power/Current Consumption		236/45	340/65	mW/mA				11
Output Short Circuit Current	-40		-120	mA	0V	0V	0V	10, 11

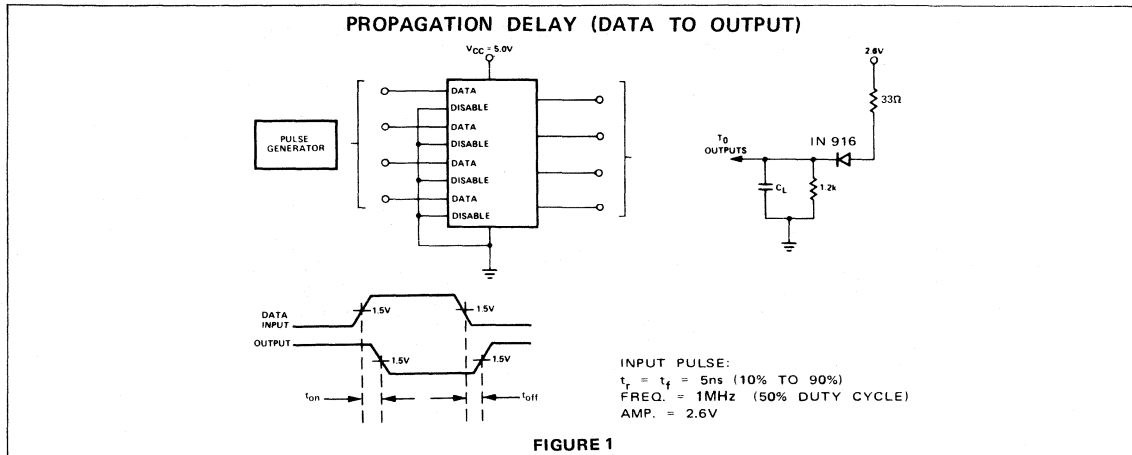
$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	DATA	DISABLE	OUTPUTS	
Propagation Delay Data to Output								
$t_{on}, t_{off}$			10	ns			30pF load	9
			20	ns			300pF load	9
Disable to Output								
High Z to 0, 0 to High Z			14	ns			30pF load	9
			22	ns			300pF load	9
High Z to 1, 1 to High Z			14	ns			30pF load	9
			22	ns			300pF load	9

**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Measurements apply to each output and the associated data input independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figures.
- Not more than one output should be shorted at a time.
- $V_{CC} = 5.25$  volts.

**AC TEST FIGURES AND WAVEFORMS**



AC TEST FIGURES AND WAVEFORMS (Cont'd)

PROPAGATION DELAY  
("0" TO HIGH Z,  $t_{pLz}$ ; HIGH Z TO 0,  $t_{pzL}$ )

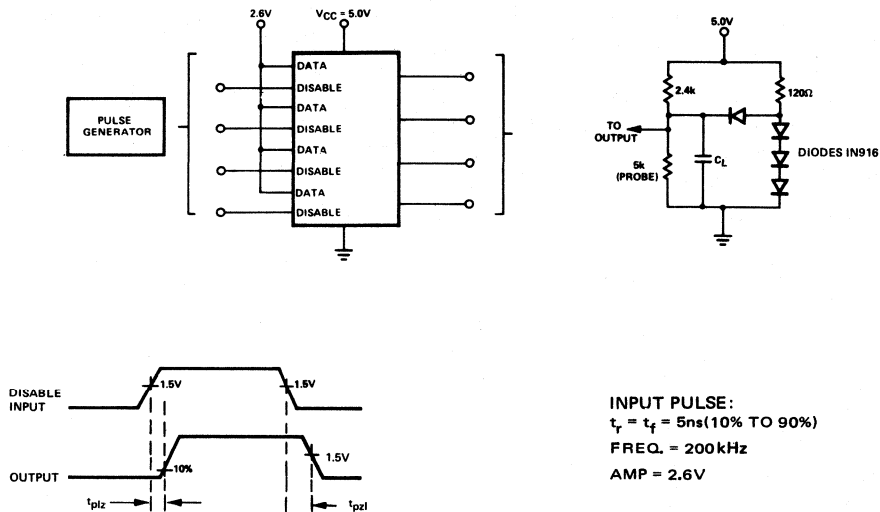


FIGURE 2

PROPAGATION DELAY  
("1" TO HIGH Z,  $t_{pHz}$ ; HIGH Z to "1",  $t_{pzH}$ )

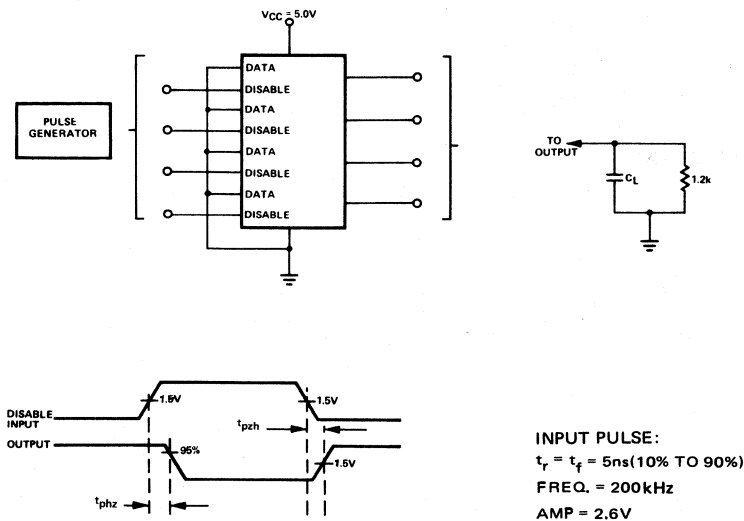
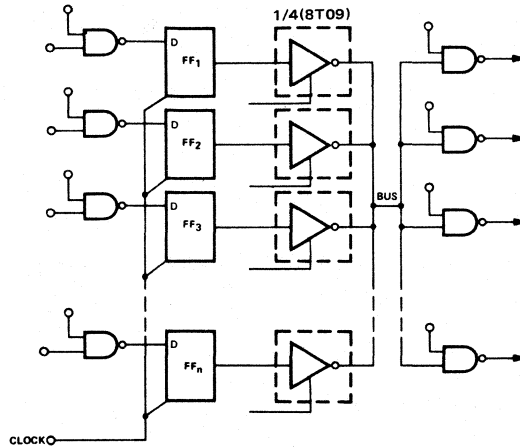


FIGURE 3

TYPICAL APPLICATION



The above figure illustrates usage of the 8T09 in data processing logic. For example, FF<sub>1</sub> thru FF<sub>n</sub> may represent bit X in each of several functions in a minicomputer (accumulators, MQ register, index registers, indirect address

registers, etc.). Transfer from any source to any load, including transfers from one register to another, can take place along the single path labeled "BUS".

DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

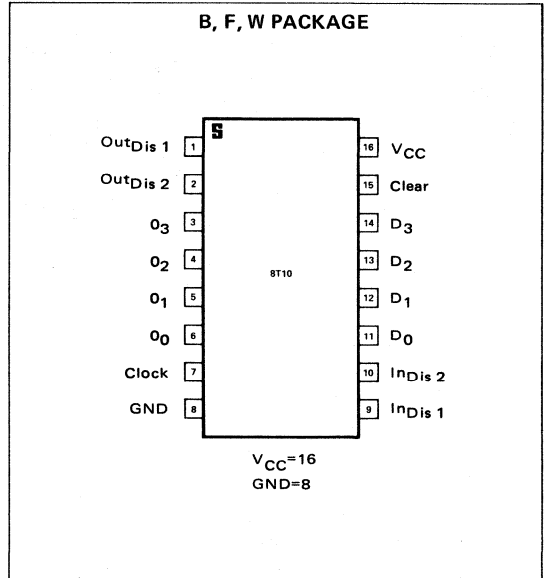
The 8T10 is a high speed Quad D flip-flop with tri-state outputs for use in bus-organized systems. The high current sink capability permits up to 20 standard loads to be interconnected on a single bus. The outputs present a high impedance to the bus when disabled (Control Input "1") and active drive when enabled (Control Inputs "0").

All four D-type flip-flops operate from a common clock with data being transferred on the low-to-high transition of the pulse.

A common clear input resets all flip-flops upon application of a logic "1" level.

Data will be stored if either one or both inputs to the Input Disable NOR gate is a logic "1".

### PIN CONFIGURATION (Top View)



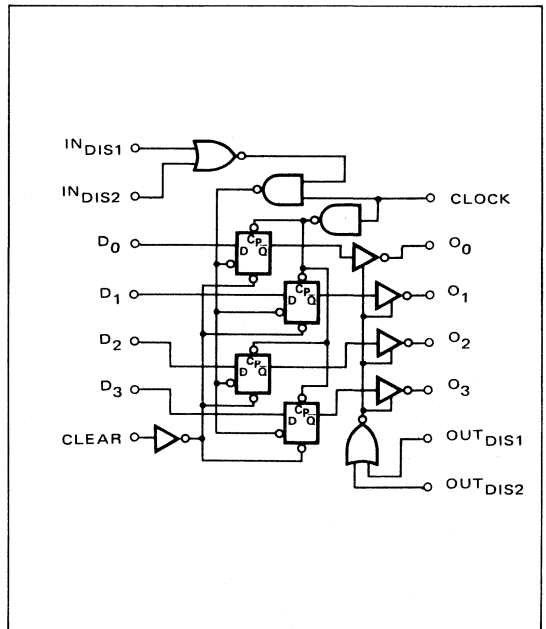
### TRUTH TABLE

$D_n$	$IN_{DIS}$	$OUT_{DIS}$	$O_{n+1}$
0	0	0	0
1	0	0	1
X	1	0	$O_n$
X	X	1	High Z

$O_n$  refers to the output state before a clock pulse.

$O_{n+1}$  refers to the output state after a clock pulse.

### LOGIC DIAGRAM





**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS								NOTES
	MIN.	TYP.	MAX.	UNITS	D <sub>n</sub>	IN DIS 1	IN DIS 2	OUT DIS 1	OUT DIS 2	CLEAR	CLOCK	OUTPUT	
"1" Output Voltage	2.4	3.0		V	2.0V	0.8V	0.8V	0.8V	0.8V	0.8V	Pulse	-5.2mA	6
"0" Output Voltage			0.4	V	0.8V	0.8V	0.8V	0.8V	0.8V	0.8V	Pulse	32mA	7
Output Leakage Current (High Impedance State)	-40		+40	μA		0.8	0.8V	+2.0V	+2.0V	0.8V	Pulse	+0.4V/ +2.4V	
"1" Input Current													
D <sub>n</sub> Inputs			40	μA	4.5V	0.4V	0.4V	0.4V	0.4V	0.4V			
All Other Inputs			50	μA		4.5V	4.5V	4.5V	4.5V	4.5V	4.5V		
"0" Input Current													
D <sub>n</sub> Inputs	-100		-3.2	mA	0.4V								
All Other Inputs	-100		-2.0	mA		0.4V	0.4V	0.4V	0.4V	0.4V	0.4V		
Input Voltage Rating	+5.5V				10mA	10mA	10mA	10mA	10mA	10mA	10mA		

T<sub>A</sub> = 25° C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS								NOTES
	MIN.	TYP.	MAX.	UNITS	D <sub>n</sub>	IN DIS 1	IN DIS 2	OUT DIS 1	OUT DIS 2	CLEAR	CLOCK	OUTPUT	
Propagation Delay (t <sub>on</sub> , t <sub>off</sub> )													
Clock to Output													
C <sub>L</sub> = 30pf		18	25	ns									12
C <sub>L</sub> = 300pf		24	35	ns									12
Disable to Output													
High Z to Logic 0, t <sub>pZL</sub>													10, 12
State (C <sub>L</sub> = 300pf)													
Logic 0 to High Z, t <sub>pLZ</sub>													11, 12
High Z (C <sub>L</sub> = 300pf)													
Clear to Output													
C <sub>L</sub> = 30pf		15	22	ns									12
C <sub>L</sub> = 300pf		21	30	ns									12
Set Up Time, t <sub>setup</sub>													
Data	+5	-1		ns									12
Input Disable		-6	0	ns									12
Hold Time, t <sub>hold</sub>													
Data		-1	+5	ns									12
Reset Pulse Width	15			ns									12
Clock Frequency	35	50		MHz									12
Clock Pulse Width													
Positive		8	12	ns									12
Negative		8	12	ns									12
Power/Current Consumption			619/ 118	mW/mA	0.4V	0.4V	0.4V	4.5V	0.4V	0.4V	4.5V		8
Output Short Circuit Current	-40		-120	mA	4.5V	0.4V	0.4V	0.4V	0.4V	0.4V		0.0V	8, 9

NOTES

- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- V<sub>CC</sub> = 5.25V.
- NOT more than one output should be shorted at a time.
- Measured to 1.5V level of output waveform.
- Measured to 10% level of output waveform.
- Refer to AC Test Circuits.

AC TEST CIRCUITS AND WAVEFORMS

PROPAGATION DELAY  $t_{on}$ ,  $t_{off}$  (CLOCK TO OUTPUT)  
DATA SETUP TIME,  $t_{setup}$

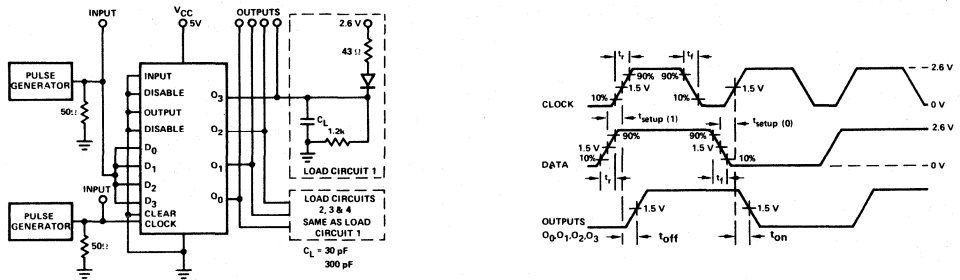


FIGURE 1

PROPAGATION DELAY (CLEAR TO OUTPUT)

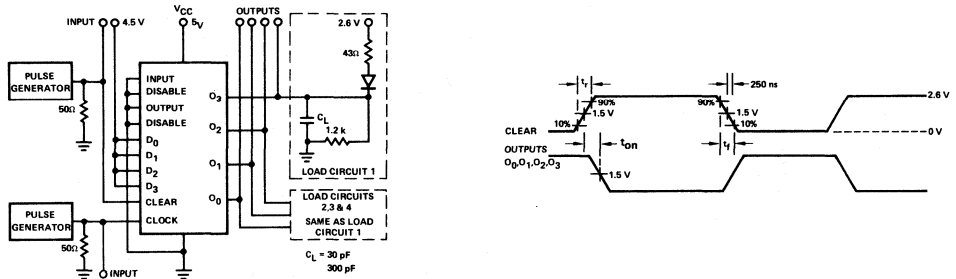


FIGURE 2

PROPAGATION DELAY (DATA HOLD TIME)

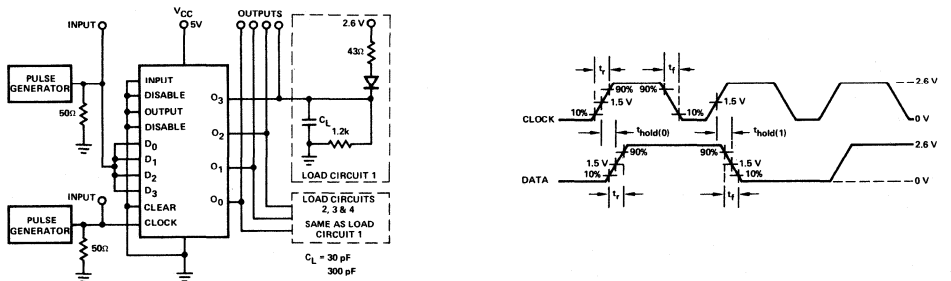


FIGURE 3

PROPAGATION DELAY (DISABLE TO OUTPUT)

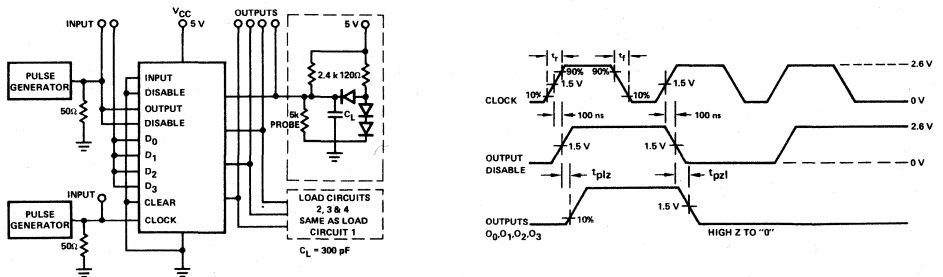
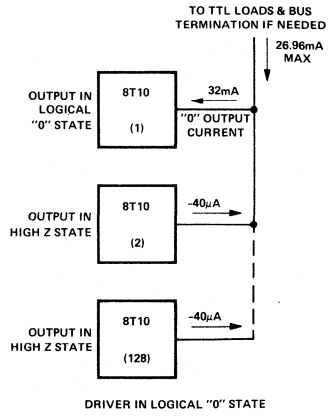
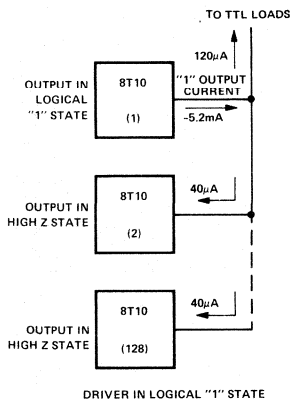
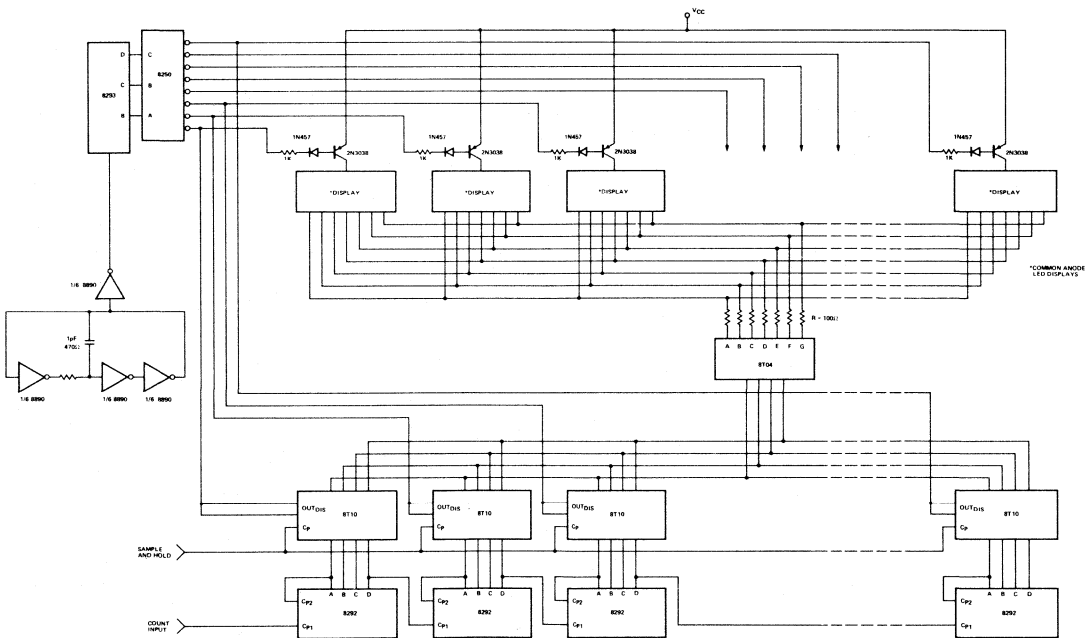


FIGURE 4

TYPICAL APPLICATIONS



MULTIPLEXING EIGHT LED DISPLAYS



### DIGITAL 8T SERIES INTERFACE TTL/MSI

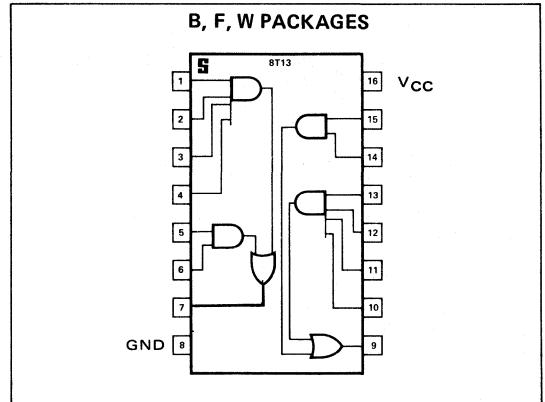
#### DESCRIPTION

The 8T13 is a monolithic Dual Line Driver designed to drive 50 ohm or 75 ohm coaxial transmission lines. TTL multiple emitter inputs allow this line driver to interface with stand-and-TTL or DTL systems. The outputs are designed to drive long lengths of coaxial cable, strip line, or twisted pair transmission lines with impedances of 50Ω to 500Ω.

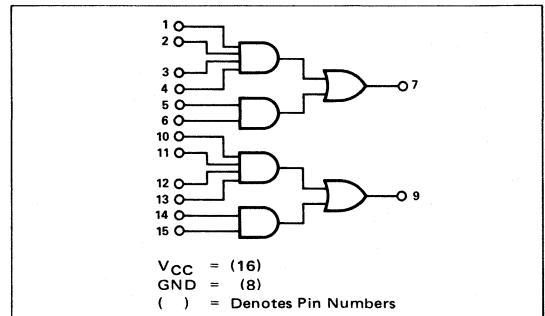
#### KEY DESIGN BENEFITS

- **High-Power Drive Capability:**  
Specified at -75mA source current rating at 2.4 volts.
- **Party-Line, Operation:**  
Emitter-follower outputs enable two or more drivers to drive the same line. This permits multiple time-shared terminal connections since these drivers have no effect upon the transmission line unless activated.
- **Input gating structure allows employment of the "OR" as well as the "AND" function.**
- **High Speed:**  $t_{on} = t_{off} = 20ns$  (max).
- **Input Clamp Diodes:** Protects inputs from line ringing.
- **Single 5 Volt power supply.**
- **Short Circuit Protection:**  
Incorporates a latch-back short circuit protection feature which protects the device by limiting the current it may source when operating under conditions of zero load resistance.

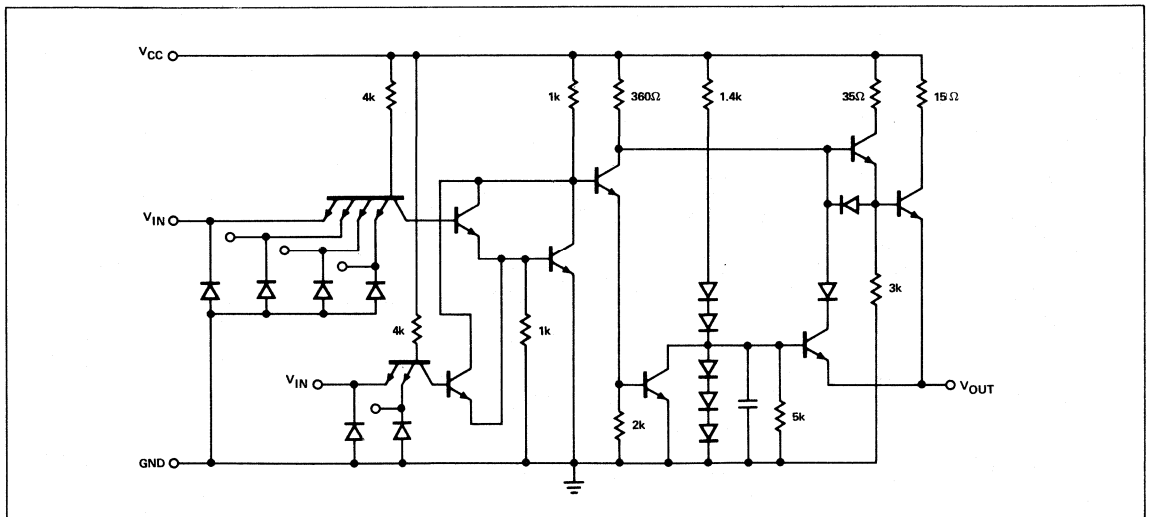
#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM



#### SCHEMATIC DIAGRAM



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				NOTES
					AND GATE #1		INPUTS OF #2 AND GATE	OUTPUTS	
	MIN.	TYP.	MAX.	UNITS	INPUT UNDER TEST	OTHER INPUTS			
"1" Output Voltage	2.4			V	2.0V	2.0V	0.8V	-75mA	6
"1" Output Leakage Current			80	$\mu$ A	0V	0V	0V	3.0V	7
"0" Output Leakage Current			-800	$\mu$ A	0.8V	4.5V	0V	0.4V	
"0" Input Current	-0.1		-1.6	mA	0.4V	4.5V			
"1" Input Current			40	$\mu$ A	4.5V	0V			

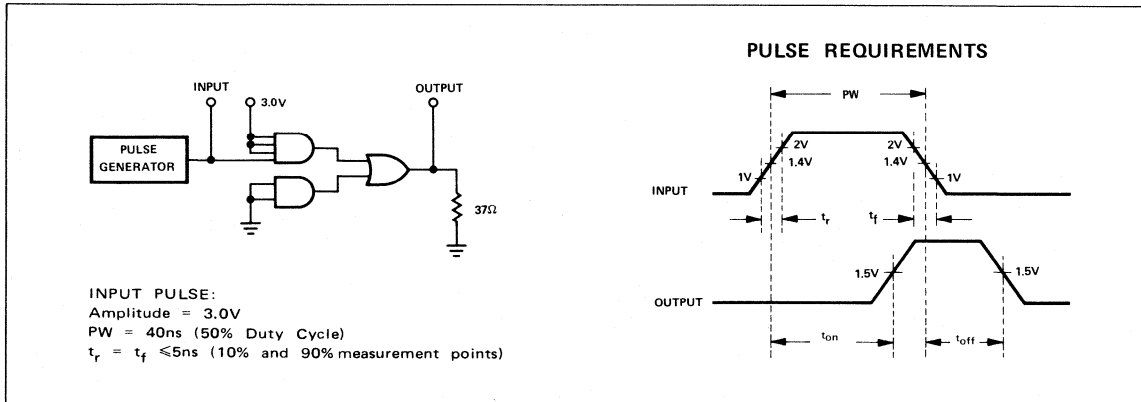
$T_A = 25^\circ \text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS				NOTES
					AND GATE NO. 1		INPUTS OF NO. 2 AND GATE	OUTPUTS	
	MIN.	TYP.	MAX.	UNITS	INPUT UNDER TEST	OTHER INPUTS			
Turn-On Delay, $t_{on}$		32	20	ns					8, 11
Turn-Off Delay, $t_{off}$		22	20	ns					9, 11
Power/Current Consumption:									
Output at "0"			315/60	mW/mA	0.8V	0.8V	0.8V		10, 13
Output at "1"			150/28	mW/mA	2.0V	2.0V	2.0V		10, 13
Input Voltage Rating	5.5			V	10mA	0V	0V		
"1" Output Current	-100		-250	mA	4.5V	4.5V	0V	2.0V	12
Output Short Circuit Current			-30	mA	4.5V	4.5V	0V	0V	12
Input Clamp Voltage			-1.5	V	-12mA				

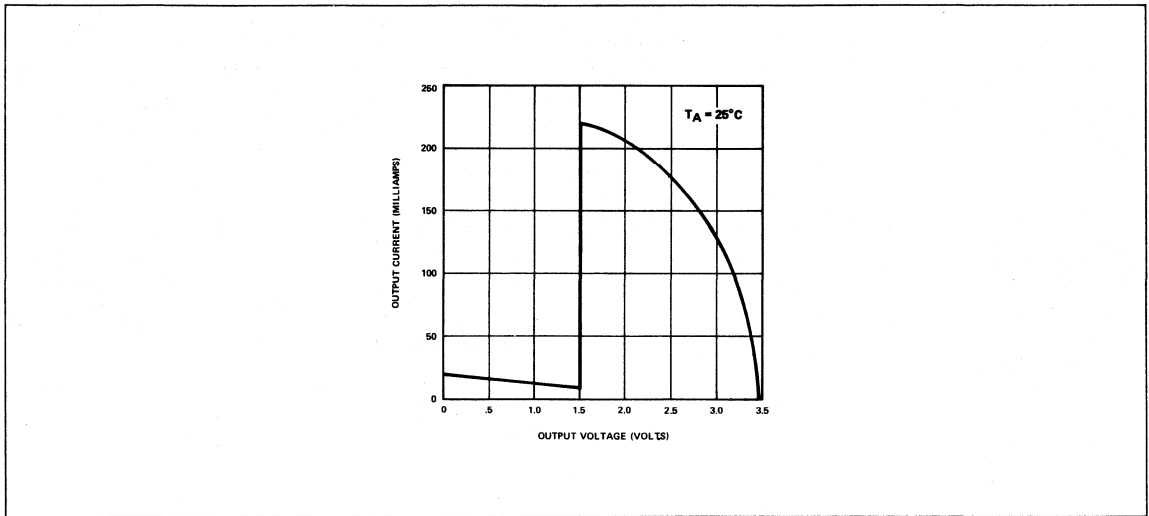
**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- With forced output voltage of 3 volts no more than 500  $\mu$ A will enter the driver when output is in "0" state.  $V_{CC} = 0\text{V}$ .
- $R_L = 37\Omega$  to ground.
- Load is  $37\Omega$  in parallel with 1000pF.
- $I_{CC}$  is dependent upon loading.  $I_{CC}$  limit specified is for no-load test condition.
- Reference AC Test Figure and Pulse Requirements.
- Reference "Typical Output Current vs Output Voltage Curve."
- $V_{CC} = 5.25$  volts. Power Consumption specified for both drivers in package.

**AC TEST FIGURE AND WAVEFORMS**



TYPICAL OUTPUT CURRENT VERSUS OUTPUT VOLTAGE CURVE



TYPICAL APPLICATIONS

A typical application for the 8T13 is shown in Figure 1. If only one line driver is to be used for each transmission

line, the line may be terminated with 50 ohms on the receiving end only. See Figure 2.

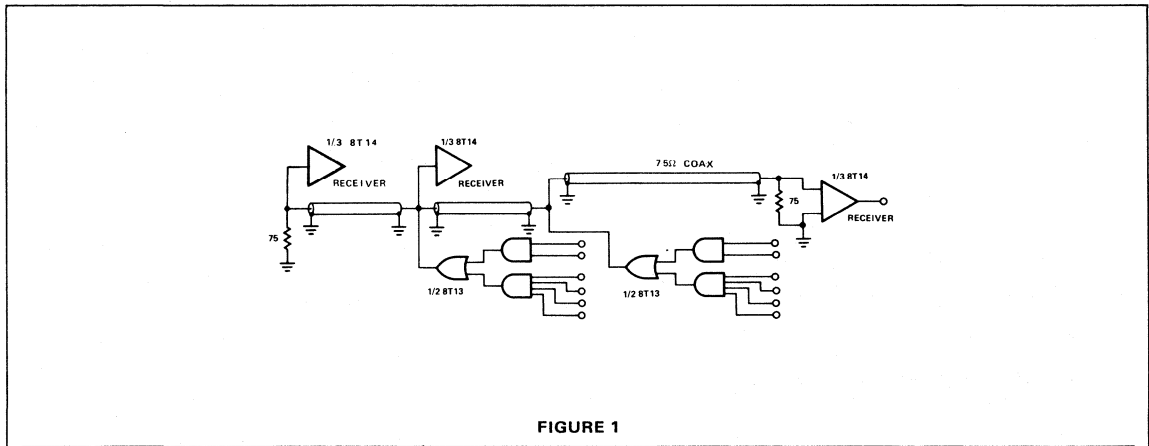


FIGURE 1

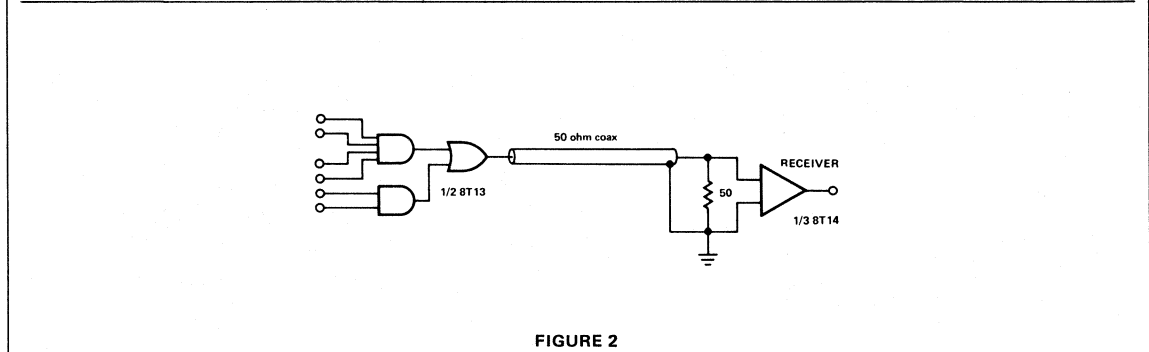


FIGURE 2

### DIGITAL 8T SERIES INTERFACE TTL/MSI

#### DESCRIPTION

The 8T14 is a Triple Line Receiver designed for applications requiring digital information to be transmitted over long lengths of coaxial cable, strip line, or twisted pair transmission lines. The Receiver's high impedance input structure ( $\approx 30k\Omega$ ) presents a minimal load to the driver circuit and allows the transmission line to be terminated in its characteristic impedance to minimize line reflections.

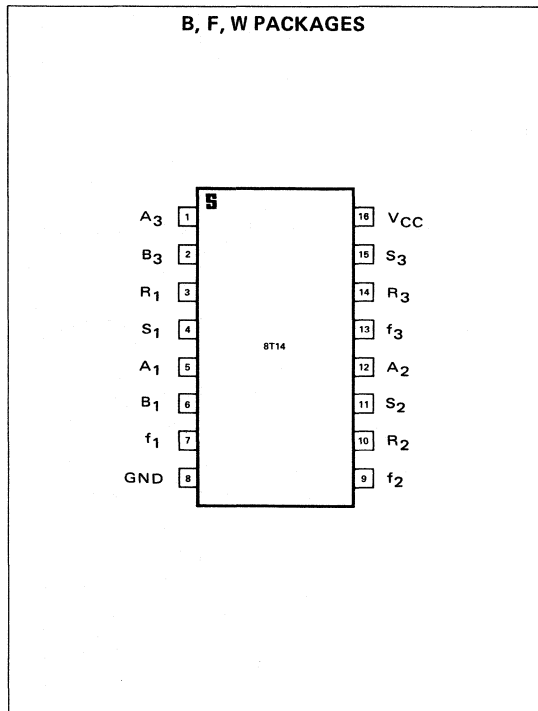
The built-in hysteresis characteristic of the 8T14 also makes it ideal for such applications as Schmitt triggers, one-shots and oscillators.

#### FEATURES

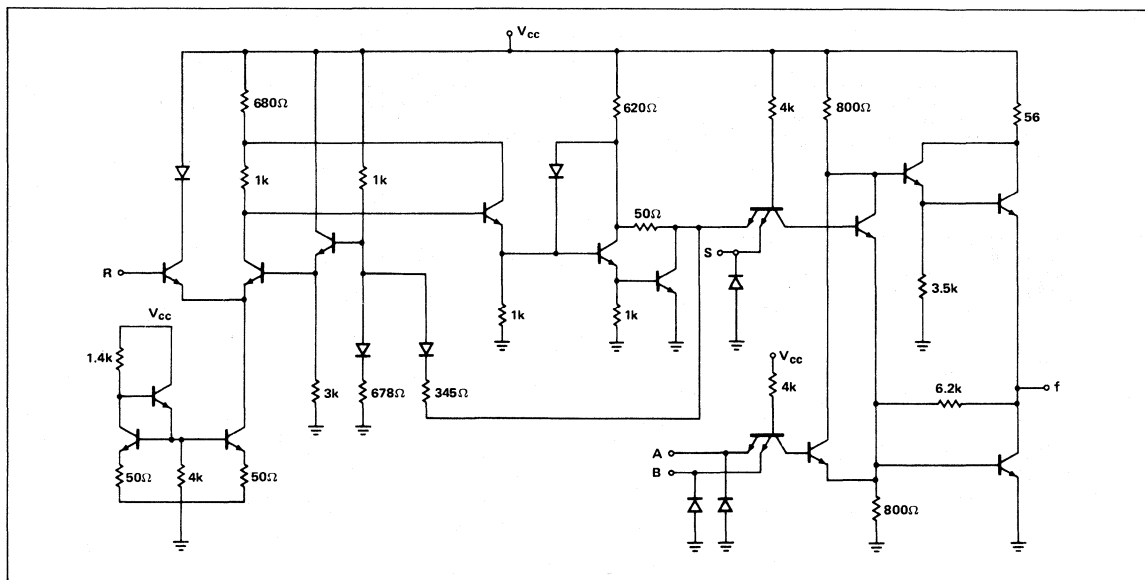
- BUILT-IN INPUT THRESHOLD HYSTERESIS\*
- HIGH SPEED:  $t_{on} = t_{off} = 20ns$  (Typical)
- EACH CHANNEL CAN BE STROBED INDEPENDENTLY
- FANOUT OF TEN (10) WITH STANDARD TTL INTEGRATED CIRCUITS
- INPUT GATING IS INCLUDED WITH EACH LINE RECEIVER FOR INCREASED APPLICATION FLEXIBILITY
- OPERATION FROM A SINGLE +5 VOLT LOGIC SUPPLY

\*Hysteresis is defined as the difference between the input thresholds for the "1" and "0" output states. Hysteresis is specified at 0.5 volts typically and 0.3 volts minimum over the operating temperature range.

#### PIN CONFIGURATION (Top View)



#### SCHEMATIC DIAGRAM



**ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	R	S	A	B	OUTPUTS	
"1" Output Voltage	2.6	3.5		V	2.0V	4.5V	0V	0V	-800μA	6, 11
	2.6	3.5		V	0V	0.8V	0V	0V	-800μA	6, 11
"0" Output Voltage			0.4	V	0.8V	2.0V	0V	0V	16mA	7, 10
			0.4	V	0V	0V	2.0V	2.0V	16mA	7, 10
"0" Input Current:										
S <sub>n</sub>	-0.1		-1.6	mA	0V	0.4V				
A <sub>n</sub>	-0.1		-1.6	mA	0V		0.4V			
B <sub>n</sub>	-0.1		-1.6	mA				0.4V		
"1" Input Current										
R <sub>n</sub>			0.17	mA	3.8V					
S <sub>n</sub>			40	μA	3.8V	4.5V				8, 9
A <sub>n</sub>			40	μA			4.5V	0V		
B <sub>n</sub>			40	μA			0V	4.5V		
Hysteresis	0.30	0.50		V		4.5V	0V	0V		8, 9

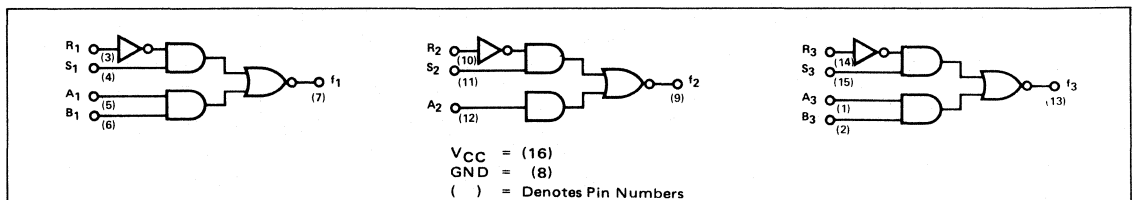
T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	R	S	A	B	OUTPUTS	
Turn-On Delay, t <sub>on</sub>		20	30	ns						
Turn-Off Delay, t <sub>off</sub>		20	30	ns						
Power/Current Consumption		315/60	380/76	mW/mA						12
Input Voltage Rating										
S	5.5			V	3.8V	10mA	0V	0V		
A	5.5			V	0V	0V	10mA	0V		
B	5.5			V	0V	0V	0V	10mA		
Output Short Circuit Current	-50		-100	mA	3.8V	0V	0V	0V	0V	12, 13
Input Clamp Voltage:										
S			-1.5	V		-12mA				
A			-1.5	V			-12mA			
B			-1.5	V				-12mA		

NOTES

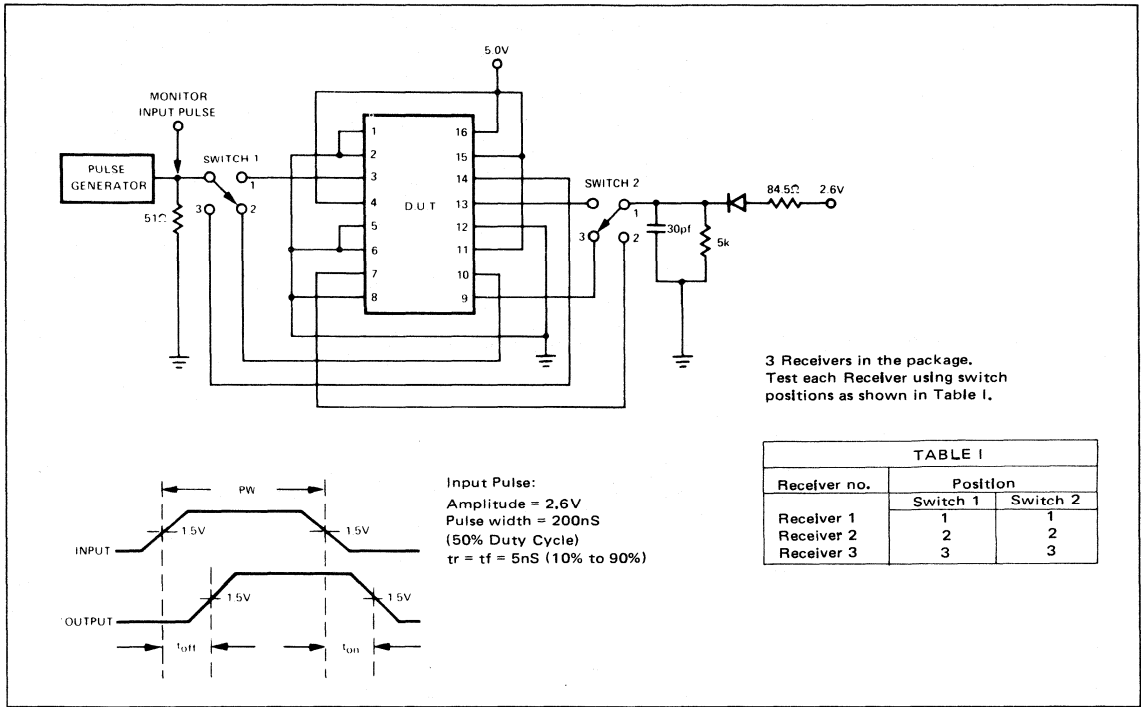
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive current flow is defined as into the terminal referenced.
- Positive Logic Definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Hysteresis is defined as voltage difference between R input level at which output begins to go from "0" to "1" state and level at which output begins to go from "1" to "0". Refer to Hysteresis Test Circuit.
- V<sub>CC</sub> = 5.0V.
- Previous condition is a "1" output state.
- Previous condition is a "0" output state.
- V<sub>CC</sub> = 5.25 volts.
- Not more than one output should be shorted at a time.
- Refer to AC Test Circuit and waveforms.

LOGIC DIAGRAMS

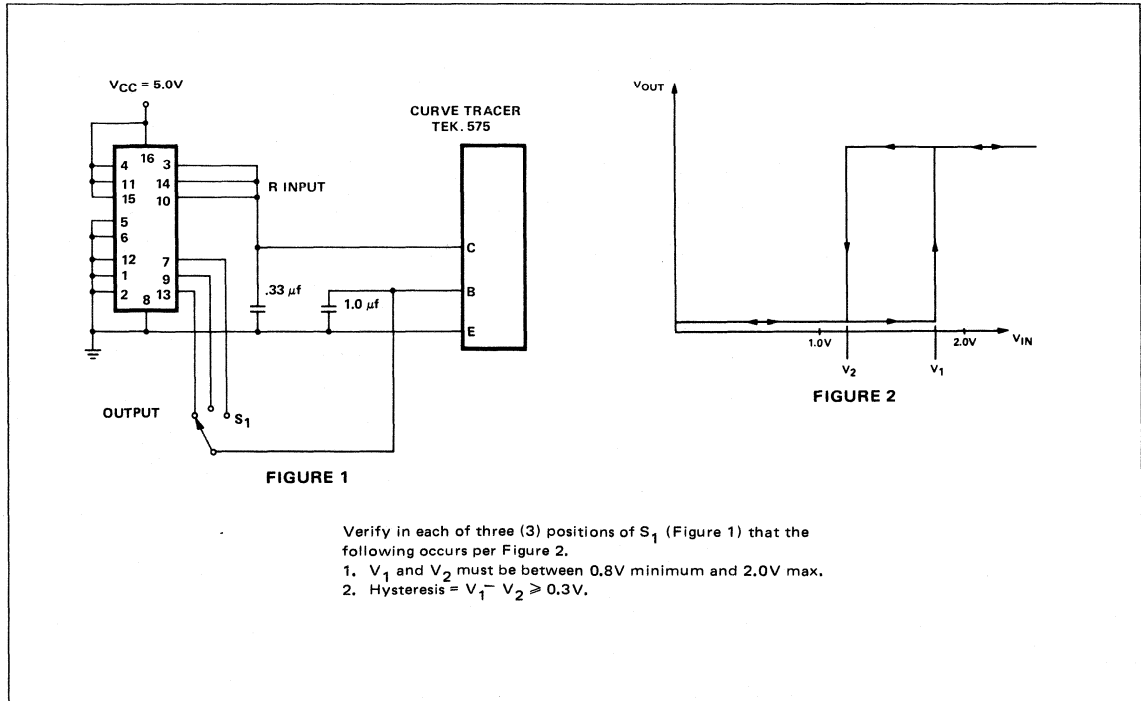




AC TEST CIRCUIT AND WAVEFORMS

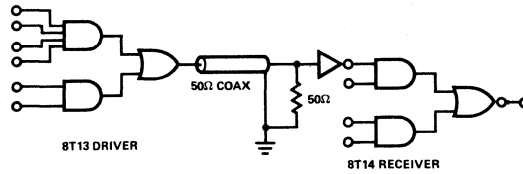


HYSTERESIS TEST CIRCUIT

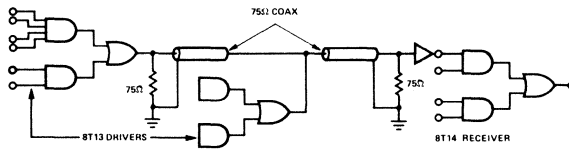


TYPICAL APPLICATIONS

COAXIAL TRANSMISSION SYSTEM

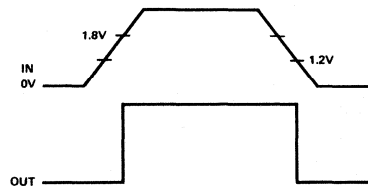
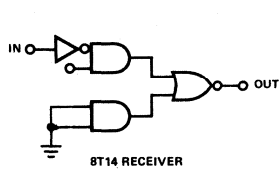


PARTY-LINE APPLICATION



If more than one driver/receiver is to be used for each transmission line, the line should be terminated at both ends as shown in Fig. 2.

SCHMITT TRIGGER APPLICATION



PRODUCT AVAILABLE IN 0°C TO +75°C TEMPERATURE RANGE ONLY

### DIGITAL 8T SERIES INTERFACE TTL/MSI

#### DESCRIPTION

The 8T15 Dual Communications Line Driver provides line driving capability for data transmission between Data Communication and Terminal Equipment. The device meets or exceeds the requirements of EIA Standard RS-232B and C, MIL STD-188B and CCITT V 24.

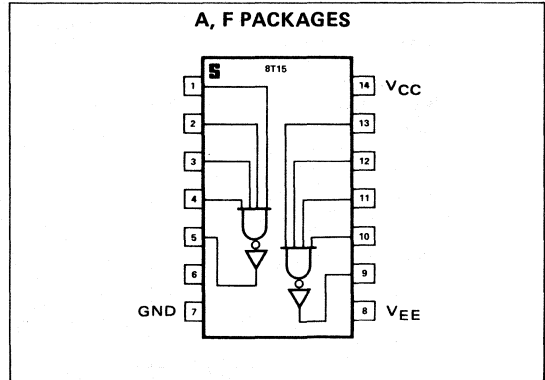
This dual 4-input NAND driver will accept standard TTL logic level inputs and will drive interface lines with nominal data levels of +6V and -6V. Output slew rate may be adjusted by attaching an external capacitor from the output terminal to ground. The outputs are protected against damage caused by accidental shorting to as high as  $\pm 25V$ .

#### ABSOLUTE MAXIMUM RATINGS\*

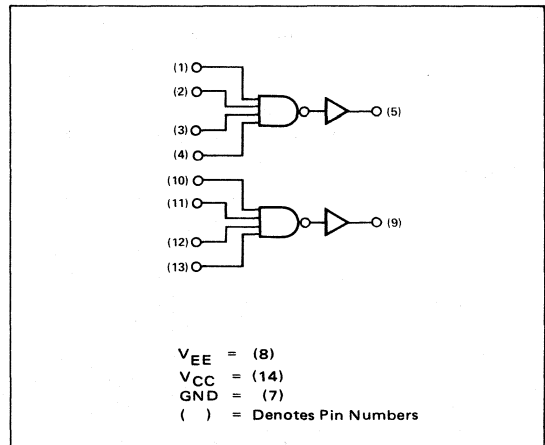
Input Voltage	+5.5V
Output Voltage	$\pm 25V$
V <sub>CC</sub>	+15V
V <sub>EE</sub>	-15V
Storage Temperature	-65°C to +150°C
Operating Temperature	0°C to +75°C

\*Limiting values above which serviceability may be impaired.

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM



#### ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUTS	
					DRIVEN	OTHER		
"1" Output Voltage	+5.0	+6.0	+7.0	V	0.8V	0.0V	-4.0mA 4.0mA	
"0" Output Voltage	-5.0	-6.0	-7.0	V	2.0V			
"0" Input Current	-0.1	-0.8	-1.6	mA	0.4V			
"1" Input Current			40	$\mu A$	4.5V			

# SIGNETICS DUAL COMMUNICATIONS EIA/MIL LINE DRIVER ■ 8T15

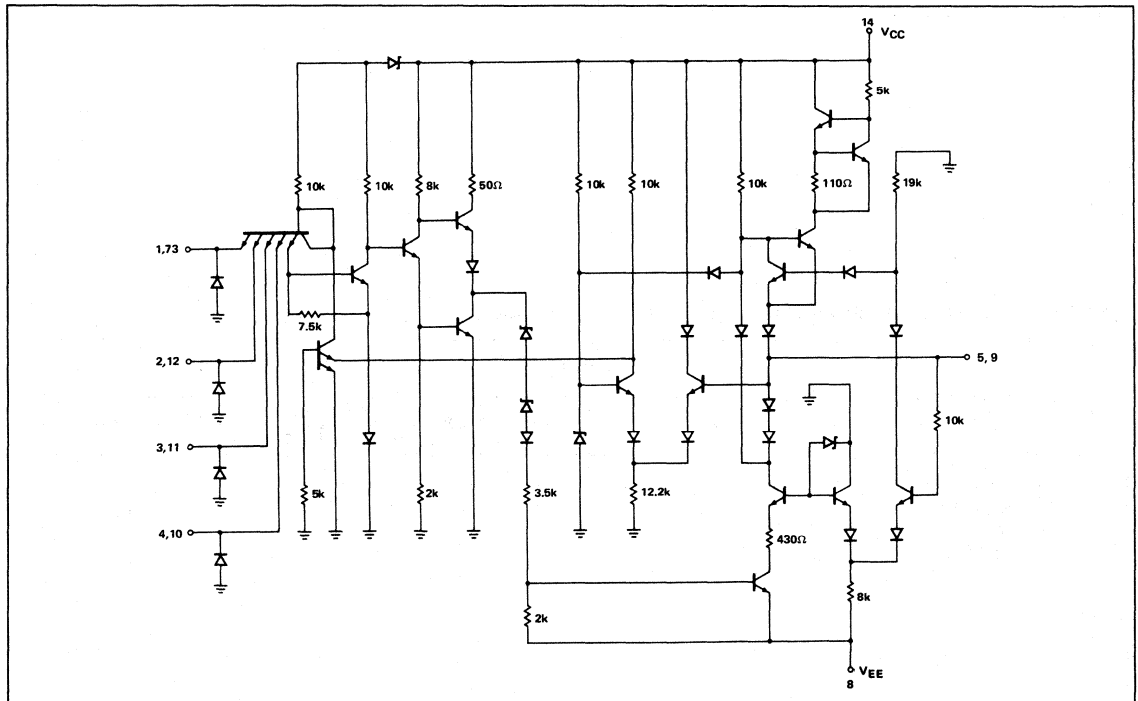
$T_A = 25^{\circ}\text{C}$ ,  $V_{CC} = +12.0\text{V}$ ,  $V_{EE} = -12.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUTS	
					DRIVEN	OTHER		
Output Rise Time	200		4	$\mu\text{s}$			Load A	7, 8
Output Fall Time			4	$\mu\text{s}$			Load B	7, 8
Output Rise Time				ns			Load C	7, 8
Output Fall Time				ns			Load D	7, 8
Power Consumption (per driver)			275	mW				10
Current from Positive Supply			16	mA				10
Current from Negative Supply			28	mA				10
Input Voltage Rating	5.5			V	10mA	0.0V		
Output Short Circuit Current			-25	mA	0.0V		-25V	9, 10
			+25	mA			+25V	9, 10
Output Impedance (Power on)		95		ohms	0.0V		-3.5 $\pm$ 1mA	
(Power on)		95		ohms	2.0V		+3.5 $\pm$ 1mA	
(Power off)	300	2.5M		ohms			$\pm$ 2V	
Input Clamp Voltage			-1.5	V	-12.0mA			

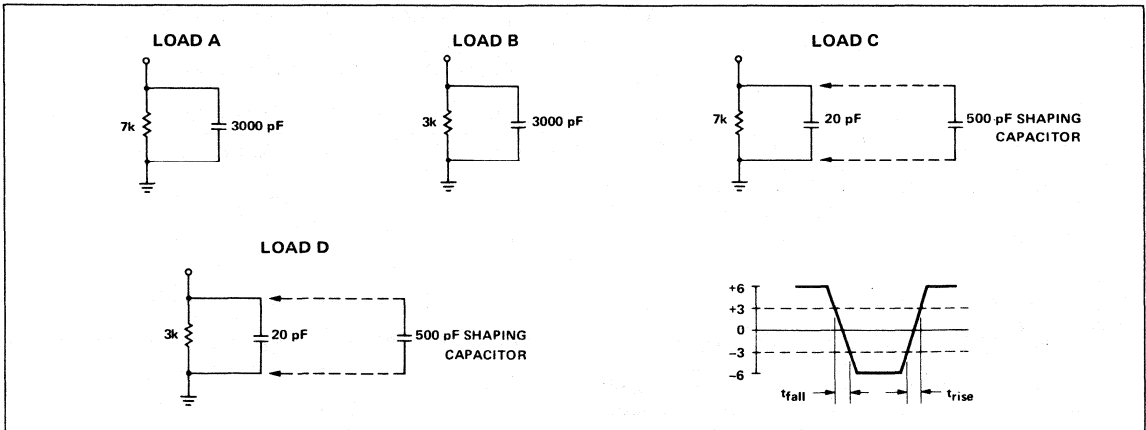
## NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Manufacturer reserves the right to make design and process changes and improvements.
- Refer to AC Test Circuits and waveforms.
- Rise and fall times are measured between the +3V and -3V points on the output waveform.
- Test each driver separately.
- $V_{CC} = +12.6\text{V}$ ,  $V_{EE} = -12.6\text{V}$

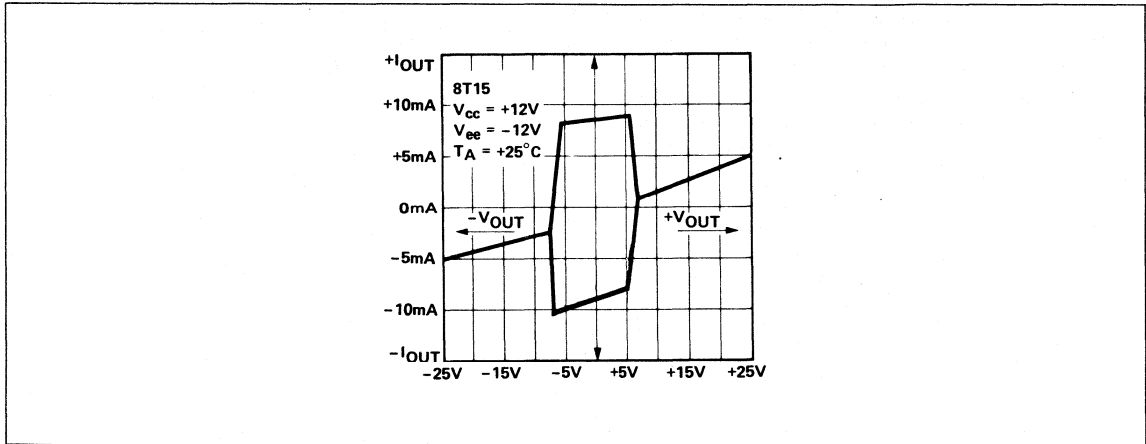
## SCHEMATIC DIAGRAM



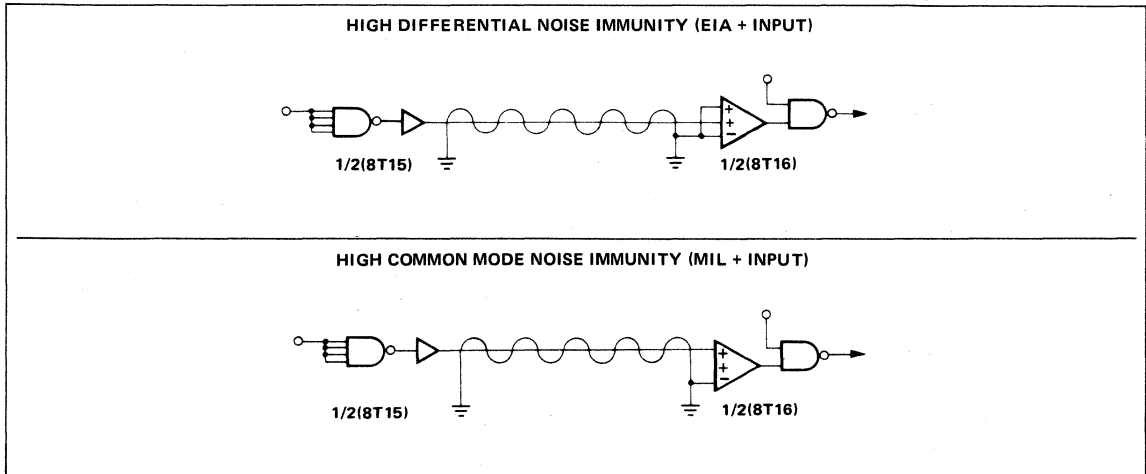
AC TEST FIGURES & WAVEFORMS



TYPICAL OUTPUT CHARACTERISTIC CURVE



TYPICAL APPLICATIONS



PRODUCT AVAILABLE IN 0° TO +75°C TEMP. RANGE ONLY.

DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

The 8T16 Dual Communications Line Receiver provides receiving capability for data lines between Data Communication and Terminal Equipment. The device meets or exceeds the requirements of EIA Standard RS-232B and C, MIL-STD-188B and CCITT V24 and operates from a single 5 volt power supply.

The receivers accept single (EIA) or double ended (MIL) inputs and are provided with an output strobing control. Both EIA and MIL input standards are accommodated.

When using the EIA input terminal (with the Hysteresis terminal open), input voltage threshold levels are typically +2V and -2V with a guaranteed minimum Hysteresis of 2.4V. By grounding the "Hysteresis" terminal, the EIA input voltage threshold levels may be shifted to typically +1.0V and +2.1V with a minimum guaranteed Hysteresis of 0.75V. (Note that when using the EIA inputs, the MIL inputs—both positive and negative—must be grounded).

The MIL input voltage threshold levels are typically +0.6V and -0.6V with a minimum guaranteed Hysteresis of 0.7V. A MIL negative terminal is provided on each receiver per specification MIL-STD-188B to provide for common mode noise rejection.

Each receiver includes a strobe input so that:

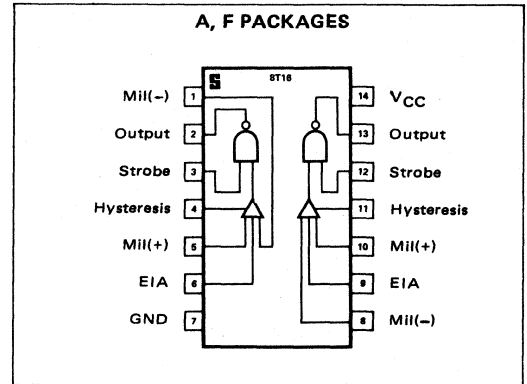
- A "1" on the strobe input allows data transfer.
- A "0" on the strobe input holds the output high.

### ABSOLUTE MAXIMUM RATINGS\*

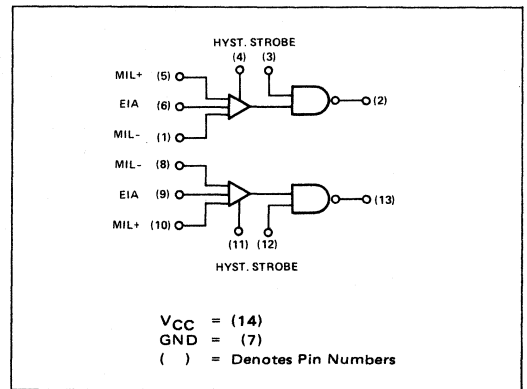
Input Voltage (EIA and MIL)	±25V
V <sub>CC</sub>	+7.0V
Storage Temperature	-65°C to +175°C
Operating Temperature	0°C to +75°C

\* Limiting values above which serviceability may be impaired.

### PIN CONFIGURATION (Top View)



### LOGIC DIAGRAM



### ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS					OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS						
					EIA	MIL (+)	MIL (-)	HYS	STROBE		
"1" Output Voltage (EIA) ("Hysteresis" Open)	2.6	3.5		V	-3.0V	0V	0V		2.0V	-800μA	8, 12
"1" Output Voltage (EIA) ("Hysteresis" grounded)	2.6	3.5		V	+0.3V	0V	0V	0V	2.0V	-800μA	8, 10
"1" Output Voltage (MIL)	2.6	3.5		V		-0.1mA	0V		2.0V	-800μA	8, 11
	2.6	3.5		V		-0.9V	0V		2.0V	-800μA	8, 11
"1" Output Voltage (Strobe)	2.6	3.5		V	+3.0V	0V	0V		0.8V	-800μA	8
"0" Output Voltage (EIA) ("Hysteresis" Open)			0.4	V	+3.0V	0V	0V		2.0V	9.6mA	9, 12
"0" Output Voltage (EIA) ("Hysteresis" grounded)			0.4	V	+3.0V	0V	0V	0V	2.0V	9.6mA	9, 12
"0" Output Voltage (MIL)			0.4	V		+0.1mA	0V		2.0V	9.6mA	9, 13
			0.4	V		+0.9V	0V		2.0V	9.6mA	9, 13

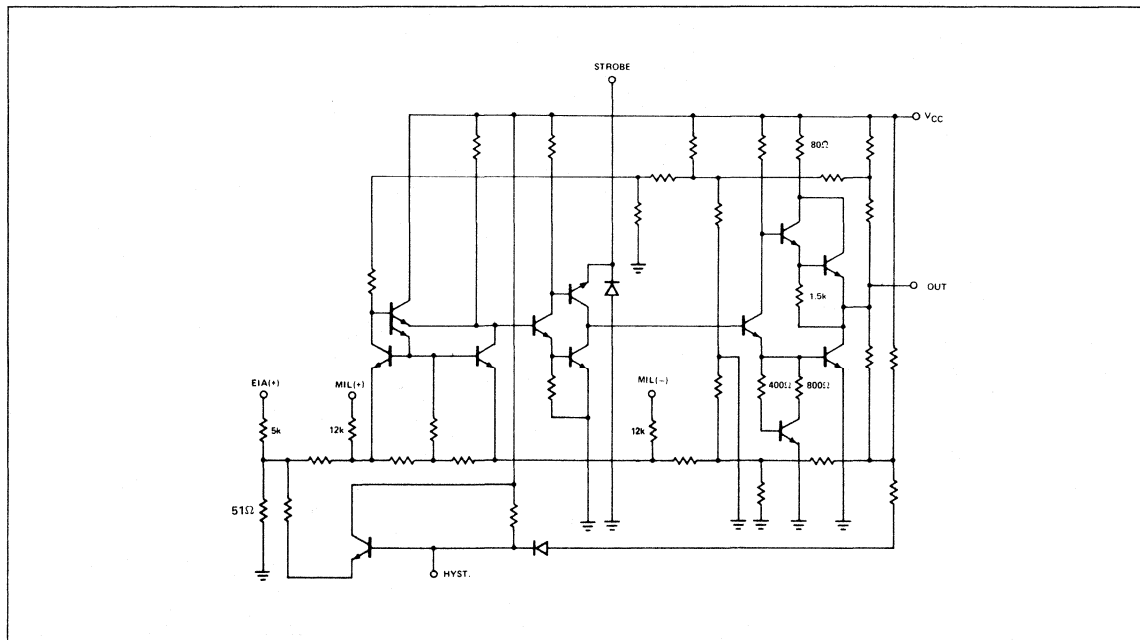
# SIGNETICS DUAL COMMUNICATIONS EIA/MIL LINE RECEIVER WITH HYSTERESIS ■ 8T16

$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$  (Cont'd)

CHARACTERISTICS	LIMITS				TEST CONDITIONS					OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS						
					EIA	MIL(+)	MIL(-)	HYS	STROBE		
"1" Output Voltage (EIA) ("Hysteresis" open)	2.8	3.5		V	+1.2V	0V	0V		2.0V	-800 $\mu$ A	8, 12
"1" Output Voltage (MIL)	2.8	3.5		V		+0.35V	0V		2.0V	-800 $\mu$ A	8, 13
"0" Output Voltage (EIA) ("Hysteresis" open)		0.2	0.4	V	-1.2V	0V	0V		2.0V	9.6mA	9, 10
"0" Output Voltage (MIL)		0.2	0.4	V		-0.35V	0V		2.0V	9.6mA	9, 11
Input Resistance (EIA)	3	5	7	k $\Omega$	$\pm 25\text{V}$	0.0V	0.0V				
Input Resistance (MIL)	7.5	11.4		k $\Omega$	0.0V	$\pm 25\text{V}$	0.0V				
Power Consumption (per receiver)		44	75	mW	3.0V	0V	0V				17
Output Short Circuit Current	-10		-70	mA	-3.0V	0.0V	0.0V		5.00V	0.0V	16, 17
Propagation Delay		100	150	ns					5.00V		14
Signal Switching Acceptance	20			kHz					5.00V		15

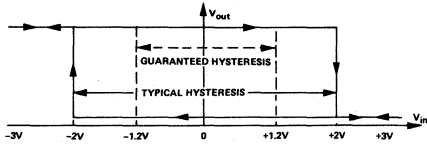
- NOTES
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
  - All measurements are taken with ground pin tied to zero volts.
  - Positive current is defined as into the terminal referenced.
  - Positive logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
  - Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
  - Manufacturer reserves the right to make design and process changes and improvements.
  - This test guarantees operation free of latch-up over the specified input voltage range.
  - Output source current is supplied through a resistor to ground.
  - Output sink current is supplied through a resistor to  $V_{CC}$ .
  - Previous EIA input: +3V (See hysteresis curve).
  - Previous MIL input: +0.9V (See hysteresis curve).
  - Previous EIA input: -3V (See hysteresis curve).
  - Previous MIL input: -0.9V (See hysteresis curve).
  - Reference AC Test Figure.
  - This test guarantees transfer of signals of up to 20kHz. Connect 1000pF between the output terminal and ground.
  - Each receiver to be tested separately.
  - $V_{CC} = 5.25\text{V}$ .

## SCHMATIC DIAGRAM

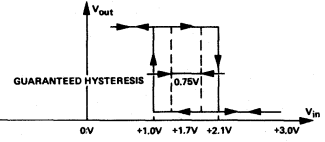


HYSTERESIS CURVES

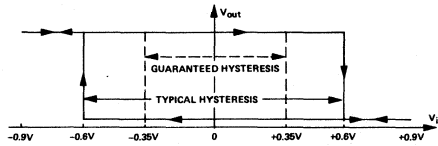
EIA – "HYSTERESIS" OPEN



EIA – "HYSTERESIS" GROUNDED

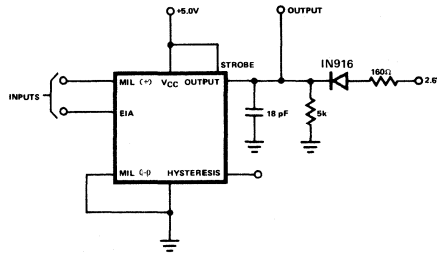


MIL – HYSTERESIS

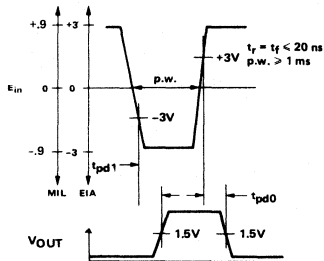


\* $V_{in}$  IS REFERENCED TO THE MIL (-) INPUT TERMINAL

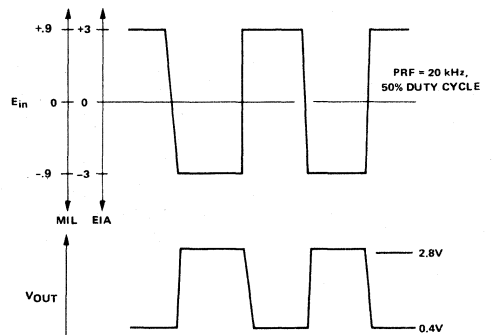
AC TEST FIGURE AND WAVEFORMS



PROPAGATION DELAY



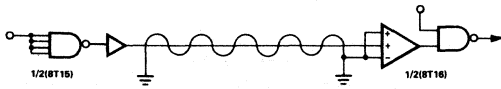
SIGNAL SWITCHING ACCEPTANCE



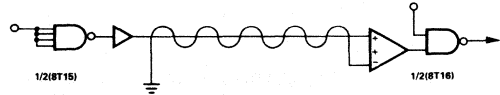


TYPICAL APPLICATIONS

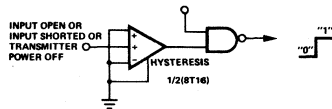
HIGH DIFFERENTIAL NOISE IMMUNITY  
(EIA + INPUT)



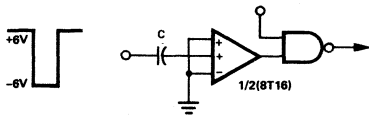
HIGH COMMON MODE NOISE IMMUNITY  
(MIL + INPUT)



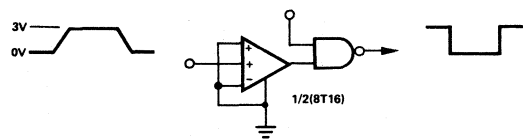
EIA FAIL-SAFE OPERATION



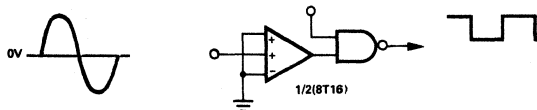
AC COUPLED OPERATIONS



SCHMITT TRIGGER



SINE TO SQUARE WAVE CONVERTER



DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

The 8T18 is a Dual 2-Input NAND Interface Gate. It is

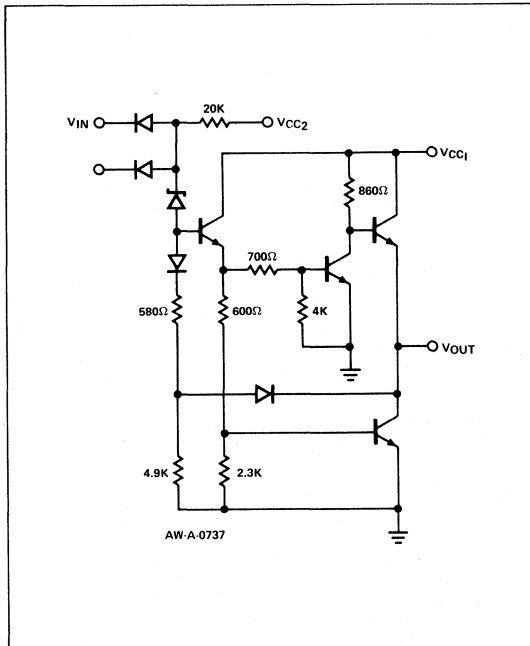
The 8T18 is a Dual 2-Input NAND Interface Gate. It is typically used as a high to low voltage translator which provides translation from up to 30-volt logic levels to standard logic levels of 5 volts.

The basic gate operates from two power supplies. The input structure functions from a high voltage supply between 20V and 30V and the second stage  $V_{CC2}$ , transistors and output structure operate from a standard 5V power supply,  $V_{CC1}$ .

The high "0" level input threshold (guaranteed at 6.5V) makes the 8T18 very attractive for noisy systems applications.

The output structure features active pull-up and pull-down, providing a low impedance driving source in both "1" and "0" output states. This configuration is particularly suited for driving the high capacitance loads encountered in high fan-out and line driving applications.

### CIRCUIT SCHEMATIC

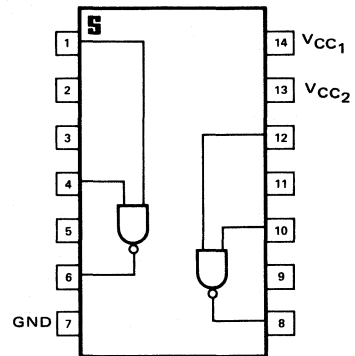


NOTE: 1/2 of unit shown. Component values are typical.

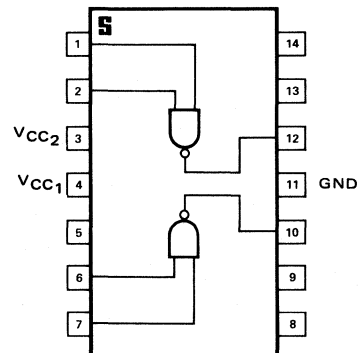
3-150

### PIN CONFIGURATIONS (Top View)

#### A, F PACKAGES



#### W PACKAGE



# DUAL 2-INPUT NAND HIGH VOLTAGE TO TTL INTERFACE GATE ■ 8T18

## DC ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS					NOTES
	MIN	TYP	MAX	UNITS	V <sub>CC1</sub>	V <sub>CC2</sub>	DRIVEN INPUT	OTHER INPUTS	OUTPUTS	
"1" Output Voltage	3.4			V	4.75V	24.0V	6.5V		-225μA	7
"0" Output Voltage			0.35	V	4.75V	20.0V	9.0V	9.0V	7.2mA	8
"0" Input Current	-0.1		1.8	mA	5.25V	24.0V	0.35V	30V		
"1" Input Current			50	μA	5.0 V	24.0V	30V	0V		
Power Consumption (per gate)										
V <sub>CC1</sub> Output "0"			44	mW	5.25V	24.0V				
V <sub>CC1</sub> Output "1"			1	mW	5.25V	24.0V	0V			
V <sub>CC2</sub> Output "0"			39	mW	5.25V	24.0V				
V <sub>CC2</sub> Output "1"			38	mW	5.25V	24.0V	0V			
Input Voltage Rating	50			V			100μA	0V		
Output Short Circuit Current		-75		mA			0V		0V	

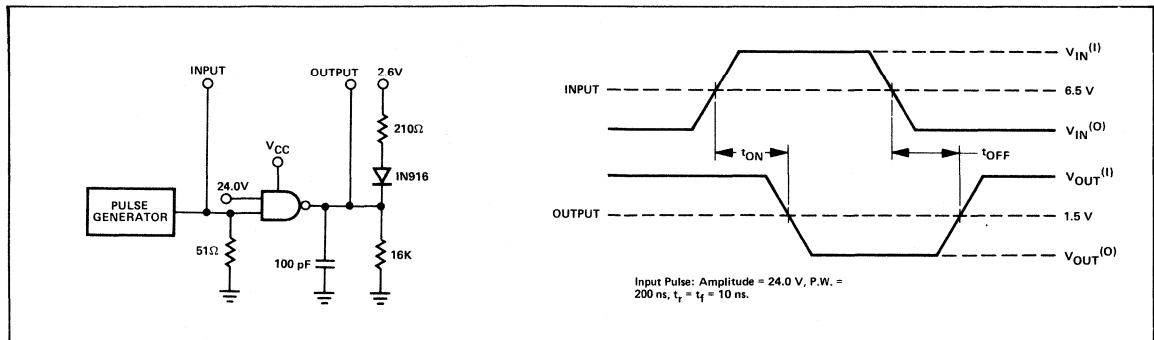
## AC ELECTRICAL CHARACTERISTICS T<sub>A</sub> = 25°C, V<sub>CC1</sub> = 5.0V, V<sub>CC2</sub> = 24.0V

CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Turn-On Delay, t <sub>on</sub>		12	20	ns	R <sub>L</sub> = 210 Ω	9
Turn-Off Delay, t <sub>off</sub>		35	70	ns	C <sub>L</sub> = 100 pF	

### NOTES

- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each gate element independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Detailed test conditions for AC testing are in Section 3.

## AC TEST FIGURE AND WAVEFORMS

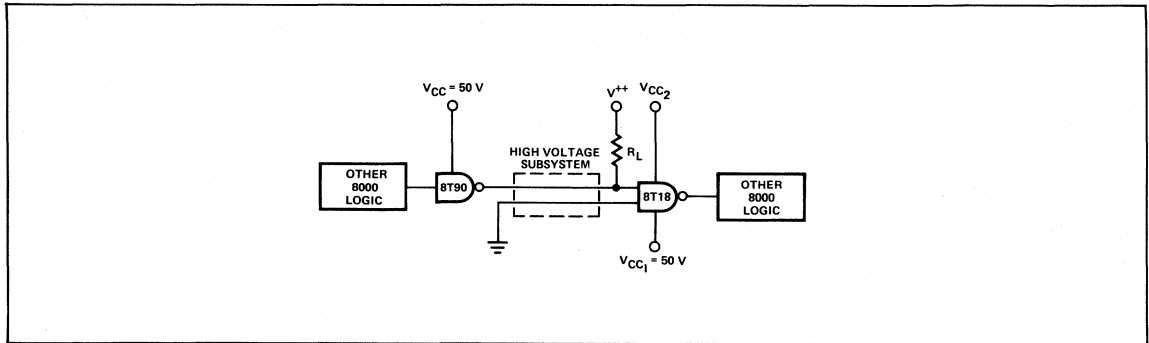


TYPICAL APPLICATION

The 8T18 provides an interface from high level (30-volt) inputs to low level (5-volt) outputs, and thus complements the 8T80 and 8T90. A typical systems application is shown.

The  $V_{CC2}$  is returned to a power supply of 20 volts or more. If  $V^{++}$  voltage exceeds 30 volts, a series current limiting resistor (to limit current to less than 2 milliamps) or a

20 to 30-volt Zener diode (shunt) must be used. The inputs of the 8T18 are rated at 50 volts reverse breakdown. The threshold voltage of the 8T18 (6.5 volt minimum) is independent of temperature since the various internal junctions are equal in number and opposite in polarity. Thus the 8T18 can be used as an accurate high-level threshold detector.



B, F PACKAGES

### DIGITAL 8000 SERIES TTL/MSI

#### DESCRIPTION

The Bidirectional One Shot is intended for applications where high speed low level signal processing is required.

The 8T20 is a Monolithic Building Block, consisting of a high speed analog comparator, digital control circuitry, and a precision monostable multivibrator. The differential input threshold voltage is between  $\pm 4mV$  with respect to the input reference level which may range from  $-3.2V$  to  $+4.2V$ . For input frequencies up to 8MHz, the device may be conditioned to act as a frequency doubler since it can trigger on both positive and negative input transitions.

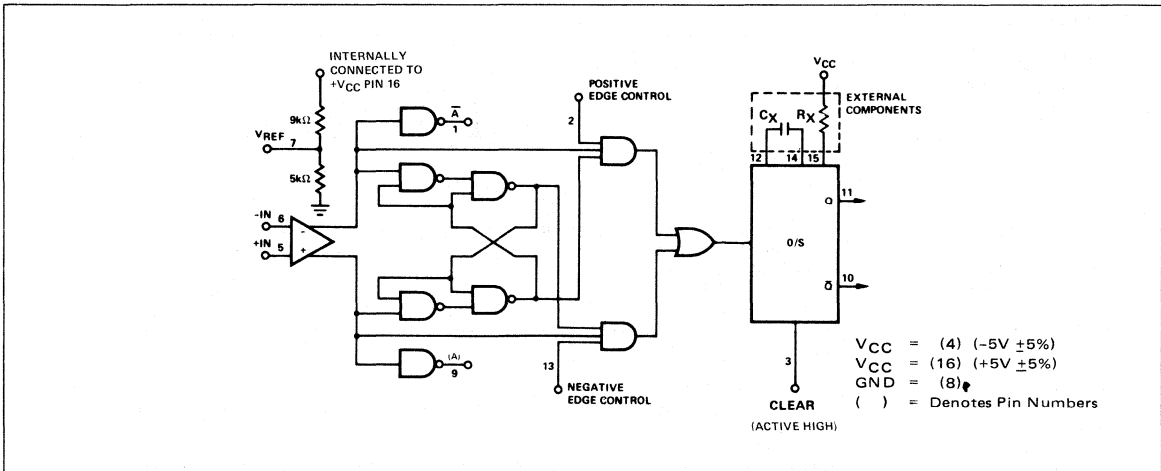
Timing pins permit using this device in a variety of applications where external control over pulse width is desirable. Pulse width ( $t_w$ ) is defined by the relationship  $t_w = C_X R_X \text{Loge}2$ . Pulse width stability is internally compensated and virtually independent of temperature and  $V_{CC}$  variations, thus only limited by the accuracy of external timing components.

An internal resistive divider is available on the chip to provide a voltage of 1.4V (typ.). This output can be connected directly to either of the comparator inputs as a reference voltage when interfacing with TTL outputs.

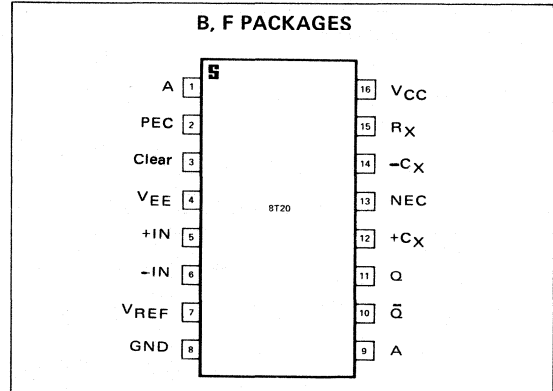
#### FEATURES

- DIFFERENTIAL INPUT THRESHOLD =  $\pm 4mV$
- PULSE POSITION ERROR = TYPICALLY  $< 3ns$
- MAX. INPUT FREQUENCY = 8 MHz
- TRIGGERS ON POSITIVE AND/OR NEGATIVE TRANSITIONS

#### LOGIC DIAGRAM



#### PIN CONFIGURATION (Top View)



#### APPLICATIONS

- DISC, TAPE AND DRUM READERS
- DIGITAL COMMUNICATIONS RECEIVERS
- SIGNAL CONDITIONERS
- TRANSITION DETECTORS

#### ABSOLUTE MAX RATINGS

- Input Voltage
- $V_{CC}$ : +7V
- $V_{EE}$ : -7V
- MAX DIFF. INPUT VOLTAGE  $\pm 5V$

# SIGNETICS BIDIRECTIONAL ONE SHOT ■ 8T20

## ELECTRICAL CHARACTERISTICS Over Recommended Temperature Range and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"1" Output Voltage (All Outputs)	2.6			V	$I_{out} = -800\mu A$	7
"0" Output Voltage (All Outputs)			0.4	V	$I_{out} = +16mA$	8
DIFFERENTIAL INPUTS						
Input Threshold Voltage ( $V_T$ )			$\pm 4$	mV		10
Input Bias Current			125	$\mu A$	Figure 5	
Input Offset Current		2		$\mu A$		
Common Mode Input Volt, Range	-3.2		+4.2	V		12
DIGITAL INPUTS						
"1" Input Current			40	$\mu A$	$V_{in} = 4.5V$	
"0" Input Current						
PEC, NEC	-0.1		-2.4	mA	$V_{in} = 0.4V$	
Clear	-0.1		-1.6	mA	$V_{in} = 0.4V$	
Input Voltage Rating (Logic Inputs)	5.5			V	$I_{in} = 10mA$	
Reference Voltage ( $V_{REF}$ )	0.8	1.4	2.0	V	Pin 7 tied to Pin 6	
Output Pulse Width, Fig. 1	10		40	ns	$R_x = 10K, C_x = \text{Open}$	11
Output Pulse Width, Fig. 3	600		800	ns	$R_x = 10K, C_x = 100pf$	11
Power Supply Current						
$I_{CC}$		37	55	mA	$V_{cc} = +5.25V$	
$I_{EE}$		-12	-20	mA	$V_{cc} = -5.25V$	
Short Circuit Current ( $I_{SO}$ )	-20		-70	mA		9

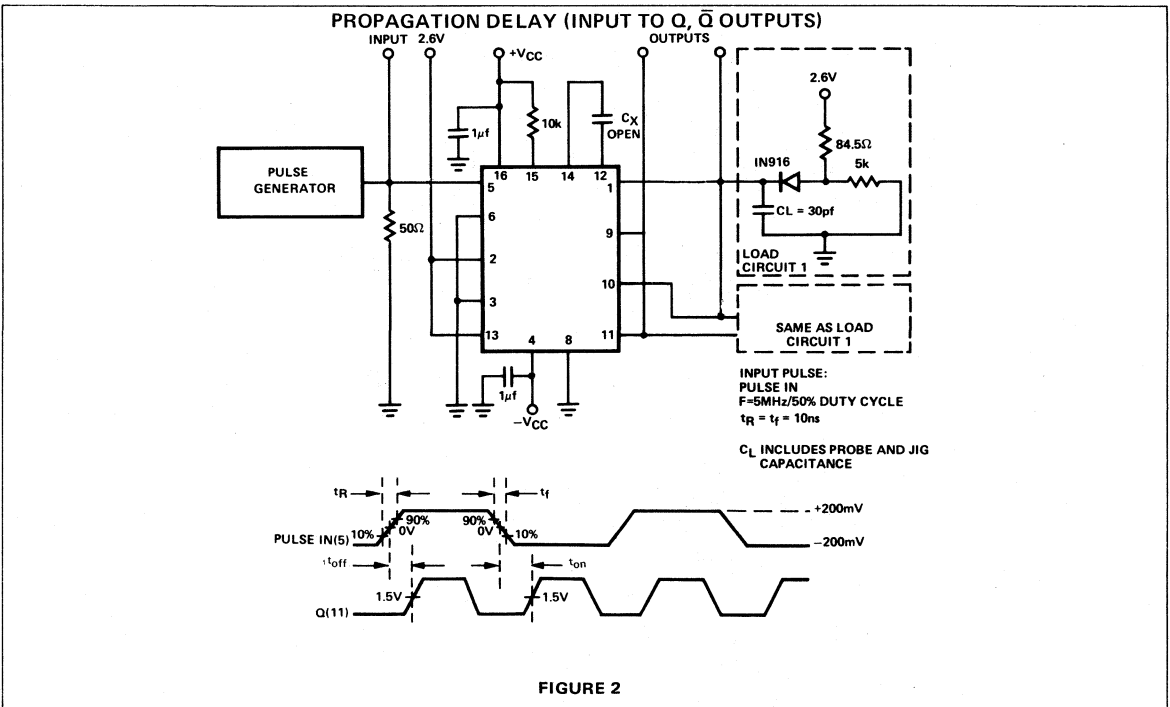
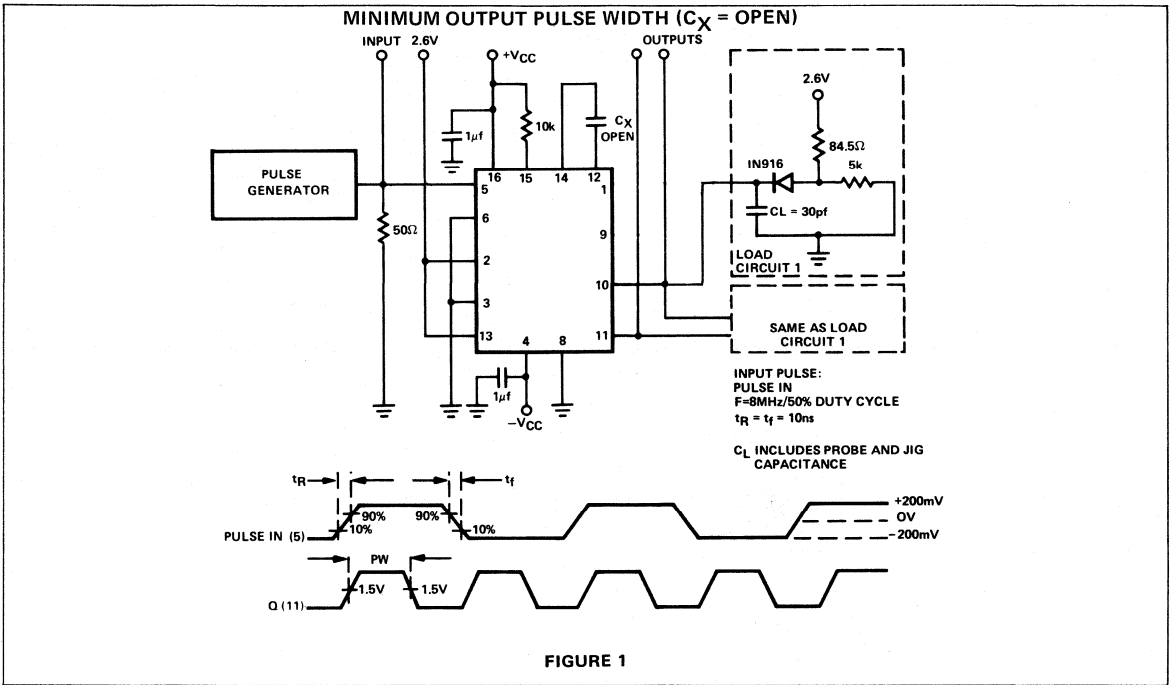
$T_A = 25^\circ C, V_{CC} = +5.00V, V_{EE} = -5.00V$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Output Frequency	16			MHz	Fig. 1, $f_{in} = 8 \text{ MHz}$	11
Propagation Delay (ton, toff)						
Input to Q, $\bar{Q}$		30	50	ns	Fig. 2	11
Input to A, $\bar{A}$		30	50	ns	Fig. 4	11
Clear to Q, $\bar{Q}$		20	30	ns		

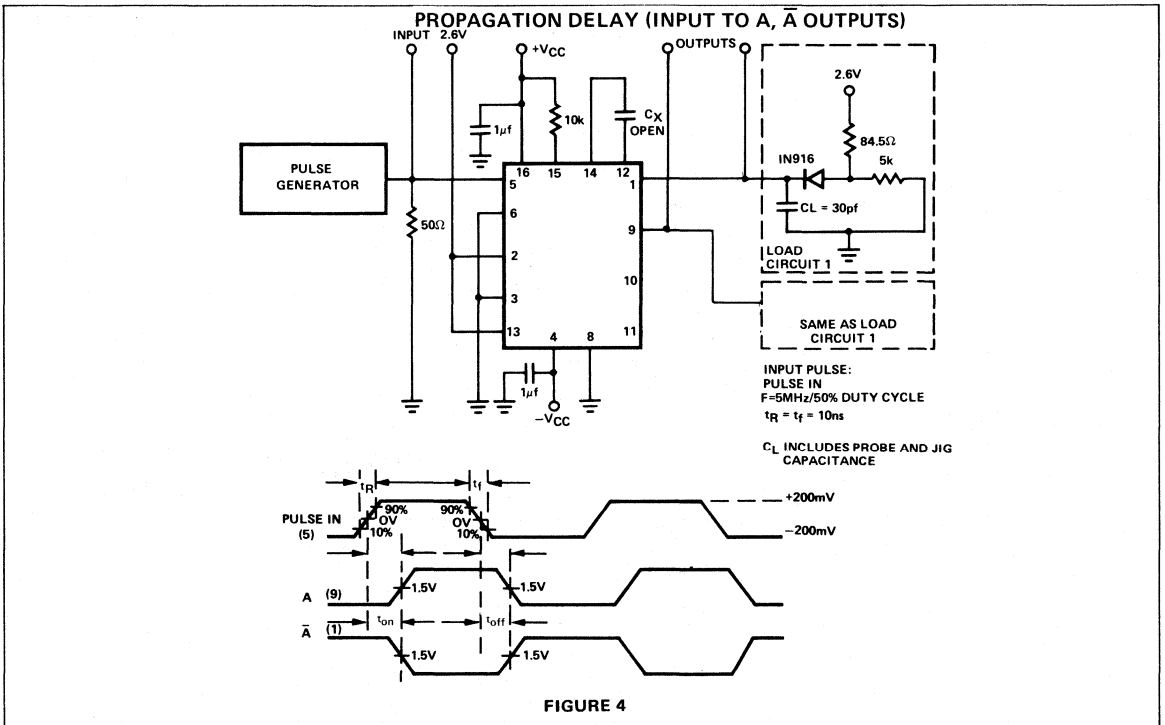
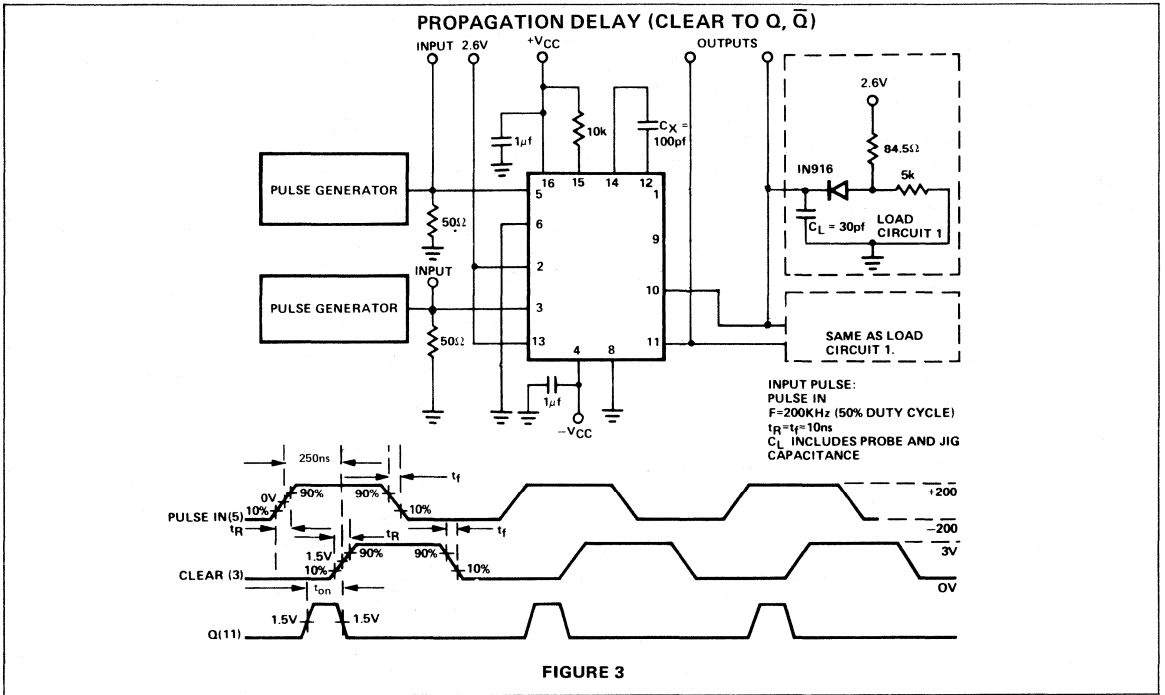
### NOTE

- All Voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Manufacturer reserves the right to make design and process changes and improvements.
- Output source current is applied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{cc}$ .
- Not more than one output should be shorted at a time.
- The differential input threshold voltage ( $V_T$ ) is defined as the maximum DC voltage deviation from the reference level necessary to trigger the one-shot.
- Refer to AC test circuits.
- Common mode voltages that are confined within the dynamic range as specified will not cause false triggering of the one-shot.

AC TEST CIRCUITS



AC TEST CIRCUITS (Cont'd)





INPUT BIAS CURRENT TEST CIRCUIT

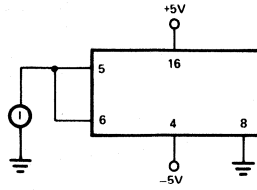
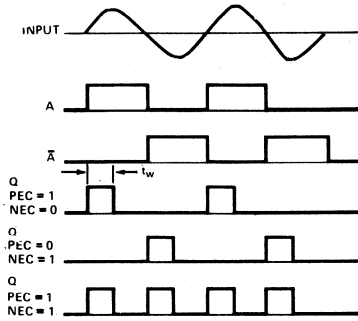


FIGURE 5

INPUT/OUTPUT WAVEFORMS



PRODUCT AVAILABLE IN 0°C TO +75°C TEMP. RANGE ONLY.

DIGITAL 8T SERIES INTERFACE TTL/MSI

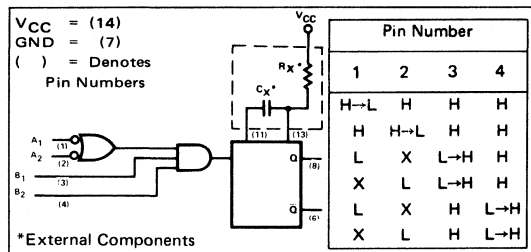
## DESCRIPTION

The Signetics N8T22A is a direct pin-for-pin replacement for the 9601 retriggerable one-shot. Triggering can be performed on either the leading or falling edge of the input signal through selection of the proper input terminal.

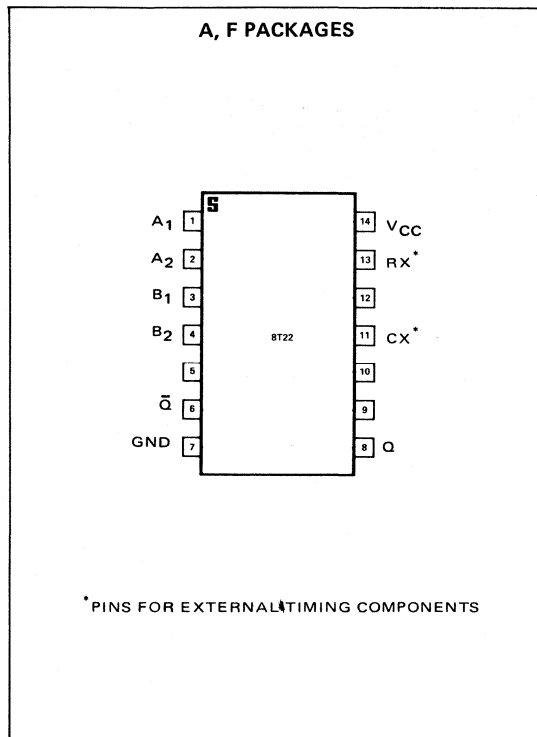
The inputs are level-sensitive making triggering independent of signal transition times. Output pulse width is determined by external timing components ( $R_x$  and  $C_x$ ) with each trigger pulse initiating a complete new timing cycle.

For those applications where a dual retriggerable one-shot is required the Signetics 9602 should be considered.

## LOGIC DIAGRAM



## PIN CONFIGURATION (Top View)



## ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
"1" Output Voltage	2.4	3.4		V	$I_{out} = -960\mu A$ $I_{out} = 12.8mA$
"0" Output Voltage		0.2	0.45	V	
Input HIGH Voltage	1.9			V	$V_{in} = 0.45V$ $V_{in} = 4.5V$
Input LOW Voltage			0.9	V	
"0" Input Current			1.6	mA	
"1" Input Current			60	$\mu A$	
Timing Resistor	5.0		50	k $\Omega$	P13 to Ground
$C_{Stray}$ - Maximum allowable wiring capacitance			50	pF	

$T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

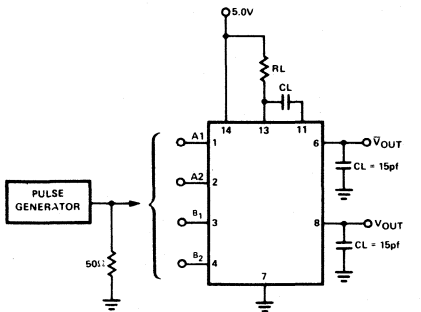
CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
Propagation Delay					
Negative Trigger Input to True Output ( $t_{pd+}$ )		25	40	ns	$R_X = 5.0\text{k}\Omega$ , $C_X = 0$ $C_L = 15\text{pF}$
Negative Trigger Input to False Output ( $t_{pd-}$ )		25	40	ns	$R_X = 5.0\text{k}\Omega$ , $C_X = 0$ $C_L = 15\text{pF}$
Min. True Output Pulse Width		45	65	ns	$R_X = 5.0\text{k}\Omega$ , $C_X = 0$ $C_L = 15\text{pF}$
Pulse Width Variation	3.08	3.42	3.76	$\mu\text{s}$	$R_X = 10\text{k}\Omega$ , $C_X = 1000\text{pF}$
Short Circuit Current	-10		-40	mA	$V_{out} = 0\text{V}$
Power Supply Current			25	mA	$V_{CC} = 5.25\text{V}$

NOTES

1. Positive current is defined as into the pin referenced.
2. Unless otherwise noted,  $10\text{k}\Omega$  resistor placed between Pin 13 and  $V_{CC}$  ( $R_X$ ).

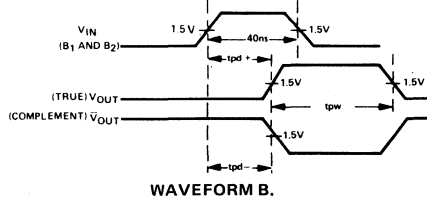
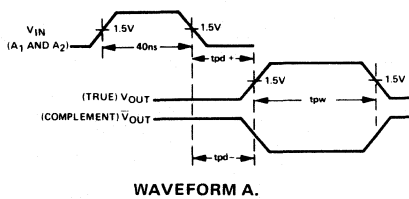
AC TEST FIGURE AND WAVEFORMS

TRIGGER INPUT/OUTPUT AND PULSE WIDTH



NOTES:

1. Pulse Generator has the following characteristics:  
 $t_r = t_f = 10\text{ns}$  (10% to 90%), AMP. = 3V.
2.  $C_L$  includes probe and jig capacitance.
3. For  $t_{pd+}$ ,  $t_{pd-}$  and  $t_{pw}$  (min.)  
 $R_X = 5\text{k}\Omega \pm 1\%$ ,  $C_X = \text{OPEN}$ , PRR = 1MHz.
4. For  $\Delta t_{pw}$ :  $R_X = 10\text{k}\Omega \pm 1\%$ ,  $C_X = 1000\text{pF} \pm 1\%$ , PRR = 200kHz.



OPERATION RULES

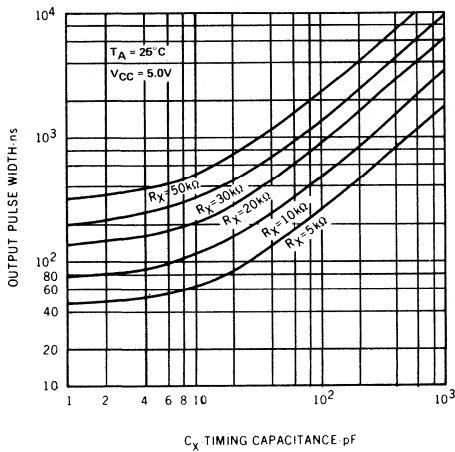
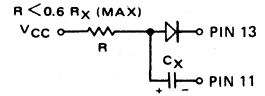
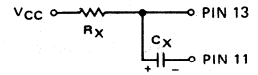
1. An external resistor ( $R_X$ ) and external capacitor ( $C_X$ ) are required as shown in the Logic Diagram.
2. The value of  $R_X$  may vary from 5.0 to 50 k $\Omega$  (0 to 75°).
3.  $C_X$  may vary from 0 to any necessary value available. If however, the capacitor has leakages approaching 3.0  $\mu$ A or if stray capacitance from either terminal to ground is more than 50 pF, the timing equations may not represent the pulse width obtained.
4. If electrolytic capacitors are to be used, the following configurations are recommended:

A. For use with low leakage electrolytic capacitors.

The normal RC configuration can be used predicably only if the forward capacitor leakage at 5.0 volts is less than 3  $\mu$ A, and the inverse capacitor leakage at 1.0 volt is less than 5  $\mu$ A over the operational temperature range, and Rule 3 above is satisfied.

B. Use with high inverse leakage current electrolytic capacitors.

The diode in this configuration prevents high inverse leakage currents through the capacitor by preventing an inverse voltage across the capacitor.



$t \approx 0.3 RC_X$

The output pulse with (t) is defined as follows

$$t = 0.32 R_X C_X \left[ 1 + \frac{0.7}{R_X} \right]$$

Where  $R_X$  is in k $\Omega$ ,  $C_X$  is in pF, t is in ns; for  $C_X < 10^3$  pF.

TYPICAL OUTPUT PULSE WIDTH VERSUS TIMING RESISTANCE AND CAPACITANCE FOR  $C_X < 10^3$  pF IS SHOWN IN THE OPPOSITE GRAPH.

0°C to +75°C

DIGITAL 8T SERIES INTERFACE TTL/MSI

## DESCRIPTION

The 8T23 is a Dual Line Driver designed to meet all of the requirements of the IBM System/360, System/370 I/O interface specifications (IBM Specification GA 22-6974-0).

The low impedance emitter follower output will drive terminated lines such as coaxial cable or twisted pair. The output is protected against accidental shorting by an internal clamping network which turns on once the output voltage drops below approximately 1.5 volts. The uncommitted emitter output structure allows Dot-OR logic to be performed as in "Party-Line" operations.

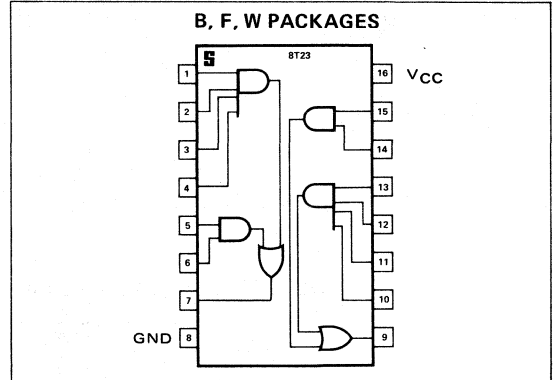
Multiple emitter inputs allow the 8T23 to interface with standard TTL or DTL systems and the circuit operates from a single +5 volt power supply.

Additional logic incorporated in the 8T23 Dual Line Driver can be used during the power-up and power-down sequence to ensure that no spurious noise is generated on the line.

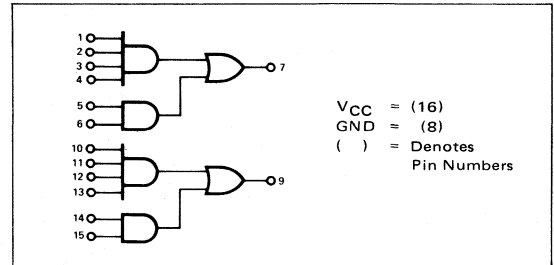
## FEATURES

- $I_{OUT} = 59.3\text{mA AT } 3.11\text{ VOLTS}$
- UNCOMMITTED EMITTER OUTPUT STRUCTURE FOR PARTY-LINE OPERATION
- SHORT-CIRCUIT PROTECTION
- SINGLE 5 VOLT POWER SUPPLY.
- AND-OR LOGIC CONFIGURATION

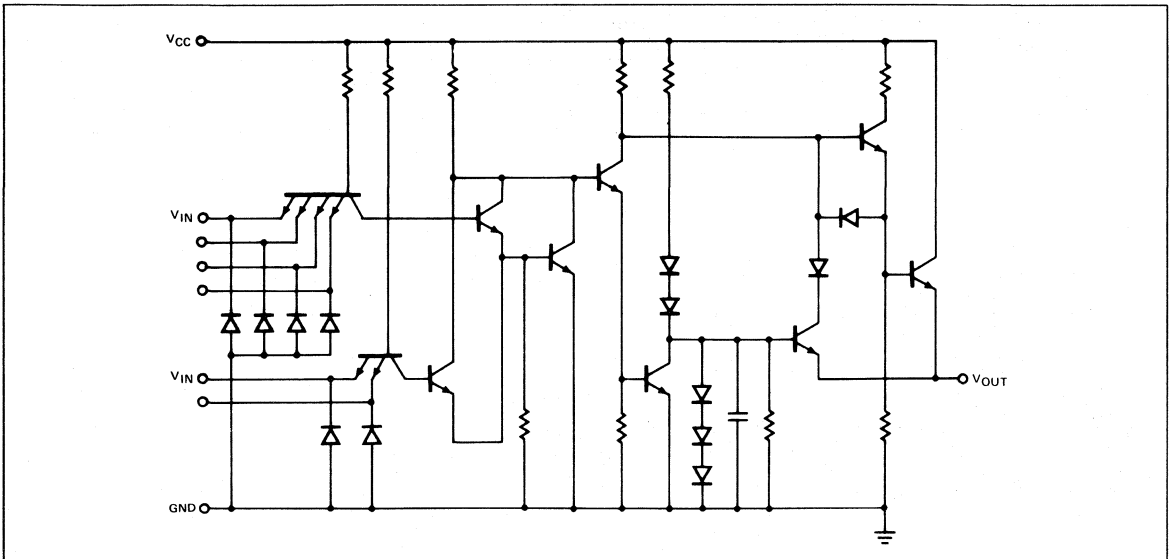
## PIN CONFIGURATION (Top View)



## LOGIC DIAGRAM



## CIRCUIT SCHEMATIC



# SIGNETICS DUAL LINE DRIVER ■ 8T23

## ELECTRICAL CHARACTERISTICS $V_{CC} = 5.0V \pm 5\%$ , $T_A = 0^\circ C$ TO $+75^\circ C$

CHARACTERISTICS	LIMITS				TEST CONDITIONS				NOTES
	MIN	TYP	MAX	UNITS	AND GATE # 1		INPUTS OF # 2 AND GATE	OUTPUT	
					INPUT UNDER TEST	OTHER INPUT			
"0" Output Voltage			+0.15	V	0.8V	4.5V	OV	-240 $\mu$ A	7
"1" Output Leakage Current			40	$\mu$ A	OV	OV	OV	3.0V	1, 13
"0" Input Current	-0.1		-1.6	mA	0.4V	4.5V			
"1" Input Current			40	$\mu$ A	4.5V	OV			

## ELECTRICAL CHARACTERISTICS $V_{CC} = 5.0V$ , $T_A = 25^\circ C$

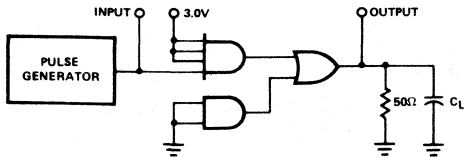
CHARACTERISTICS	LIMITS				TEST CONDITIONS				NOTES
	MIN	TYP	MAX	UNITS	AND GATE # 1		INPUTS OF # 2 AND GATE	OUTPUT	
					INPUT UNDER TEST	OTHER INPUT			
"1" Output Voltage	3.11			V	2.0V	2.0V	0.8V	-59.3mA	
Turn-On Delay, $t_{on}$		12 15	20 25	nS nS					8, 11 9, 11
Turn-Off Delay, $t_{off}$		12 20	20 35	nS nS					8, 11 9, 11
Power/Current Consumption Output at "0"			315/ 60	mW/ mA	0.8V	0.8V	0.8V		10, 14
Output at "1"			150/ 28	mW/ mA	2.0V	2.0V	2.0V		10, 14
Input Voltage Rating	5.5			V	10mA	OV	OV		
"1" Output Current	-100		-250	mA	4.5V	4.5V	OV	2.0V	12, 14
Input Clamp Voltage			-1.5	V	-12mA				

### NOTES

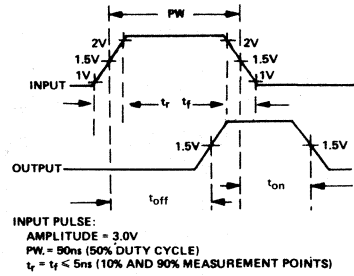
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- With forced output current of 240 $\mu$ A the output voltage must not exceed 0.15V.
- $R_L = 50\Omega$  to ground.
- Load is 50 $\Omega$  in parallel with 100pF.
- $I_{CC}$  is dependent upon loading.  $I_{CC}$  limit specified is for no-load test condition for both drivers.
- Reference AC Test Circuit and Pulse Requirements.
- Reference "Typical Output Current vs. Output Voltage Curve".
- $V_{CC} = 0.00V$ .
- $V_{CC} = 5.25V$ .

AC TEST FIGURE AND WAVEFORMS

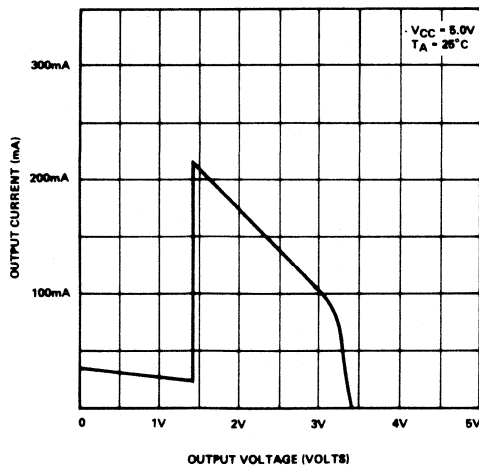
AC TEST CIRCUIT



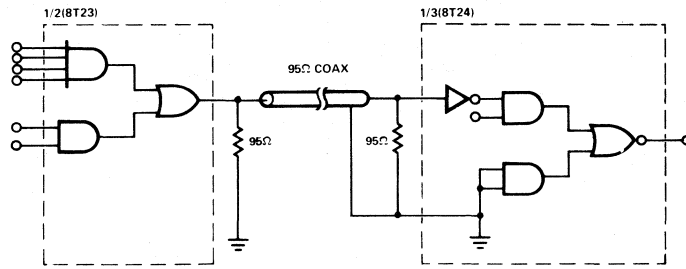
PULSE REQUIREMENTS



TYPICAL OUTPUT CHARACTERISTICS



TYPICAL APPLICATIONS





0°C TO +75°C

DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

The 8T24 is a Triple Line Receiver designed specifically to meet the IBM System/360, System/370 I/O Interface Specification (IBM Specification GA 22-6974-0). Each receiver incorporates hysteresis to provide high noise immunity and high input impedance to minimize loading on the driver circuit.

An input voltage of 1.7 volts or more is interpreted as a logical one; an input of 0.70 volts or less is interpreted as a logical zero as is an open circuited input.

The receiver input (R) of the 8T24 will not be damaged by a DC input of +7.0 volts with power on or by a DC input of +6.0 volts with power off in the receiver. The 8T24 will also withstand an input of -0.15V with power on or off.

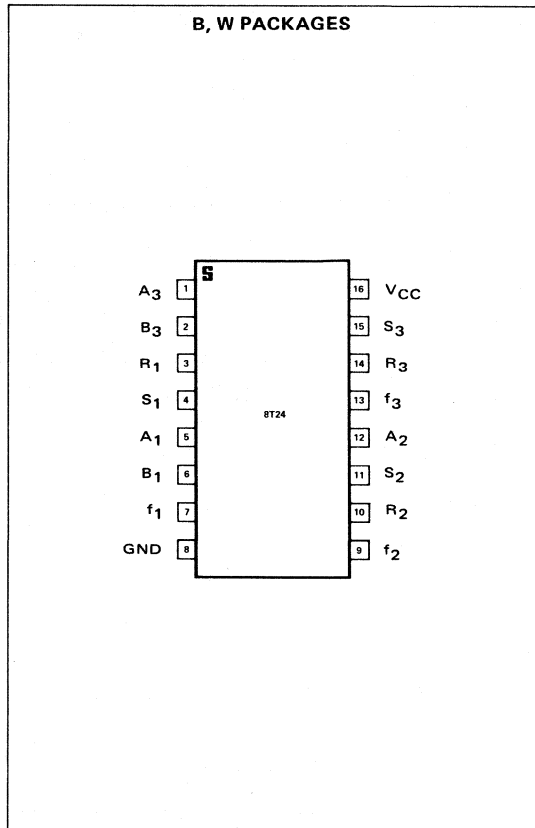
The 8T24 is fully compatible with TTL and DTL systems and operates from a single 5 volt power supply.

### FEATURES

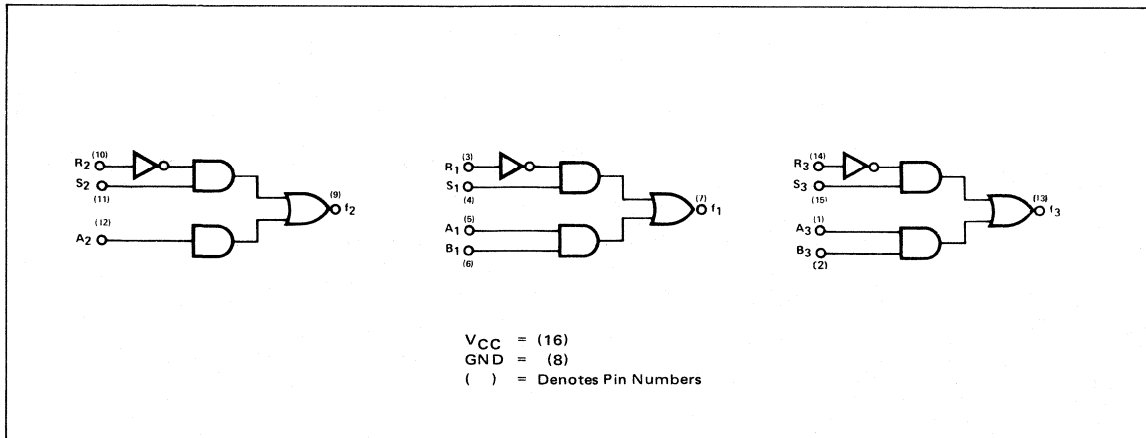
- BUILT-IN INPUT THRESHOLD HYSTERESIS\*
- HIGH SPEED:  $T_{ON} = T_{OFF} = 20\text{ns}$  (TYPICAL)
- EACH CHANNEL CAN BE STROBED INDEPENDENTLY
- FANOUT OF TEN (10) WITH STANDARD TTL INTEGRATED CIRCUITS
- INPUT GATING IS INCLUDED WITH EACH LINE RECEIVER FOR INCREASED APPLICATION FLEXIBILITY
- OPERATION FROM A SINGLE +5V POWER SUPPLY

\* Hysteresis is defined as the difference between the input thresholds for the "1" and "0" output states. Hysteresis is specified at 0.4V typically and 0.2V minimum over the operating temperature range.

### PIN CONFIGURATION (Top View)



### LOGIC DIAGRAM WITH PIN LAYOUT



# SIGNETICS TRIPLE LINE RECEIVER WITH HYSTERESIS ■ 8T24

## ELECTRICAL CHARACTERISTICS $V_{CC} = 5.0V \pm 5\%$ , $T_A = 0^\circ C$ TO $+75^\circ C$

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	R	S	A	B	OUTPUTS	
"1" Output Voltage	2.6	3.4		V	1.70V	4.5V	0V	0V	-800 $\mu$ A	7
	2.6	3.4		V	0V	0.7V	0V	0V	-800 $\mu$ A	7
"0" Output Voltage		0.2	0.4	V	0.70V	1.7V	0V	0V	16mA	8
		0.2	0.4	V	0V	0V	1.7V	1.7V	16mA	8
"0" Input Current										
$S_n$	-0.1		-1.6	mA	0V	0.4V				
$A_n$	-0.1		-1.6	mA	0V		0.4V			
$B_n$	-0.1		-1.6	mA				0.4V		
"1" Input Current			0.17	mA	3.11V					9
	$R_n$		5.0	mA	7.0V					
	$R_n$		5.0	mA	6.0V					
	$S_n$		40	$\mu$ A	3.11V	4.5V				
	$A_n$		40	$\mu$ A			4.5V	0V		
	$B_n$		40	$\mu$ A			0V	4.5V		
	$B_n$			40	$\mu$ A					

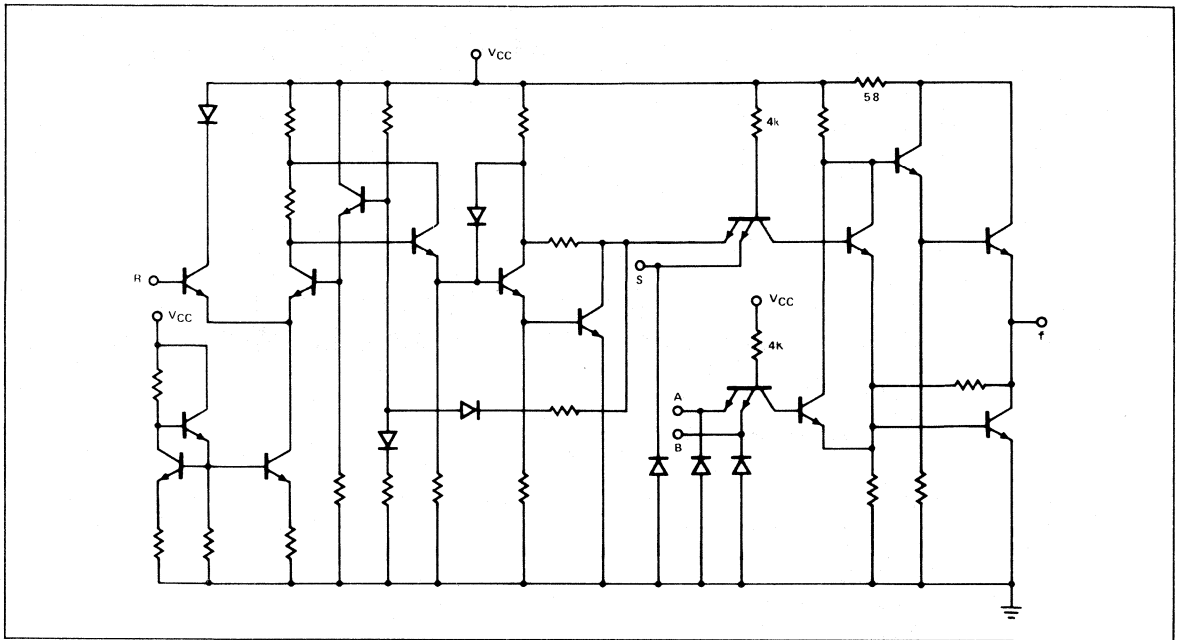
## ELECTRICAL CHARACTERISTICS AT $V_{CC} = 5.0V$ AND $T_A = 25^\circ C$

CHARACTERISTICS	LIMITS				TEST CONDITIONS					NOTES
	MIN.	TYP.	MAX.	UNITS	R	S	A	B	OUTPUTS	
Turn-On Delay, $t_{on}$		20	30	nS						13
Turn-Off Delay, $t_{off}$		20	30	nS						13
Hysteresis	0.2	0.4		V		4.5V	0V	0V		11, 12
Power/Current Consumption		315	380	mW						14
		60	72	mA						
Input Voltage Rating										
S	5.5			V	3.11V	10mA	0V	0V		
A	5.5			V	0V	0V	10mA	0V		
B	5.5			V	0V	0V	0V	10mA		
Output Short Circuit Current	-50		-100	mA	3.11V	0V	0V	0V		10, 14
Input Voltage Rating										
S			-1.5	V		-12mA				
A			-1.5	V			-12mA			
B			-1.5	V				-12mA		

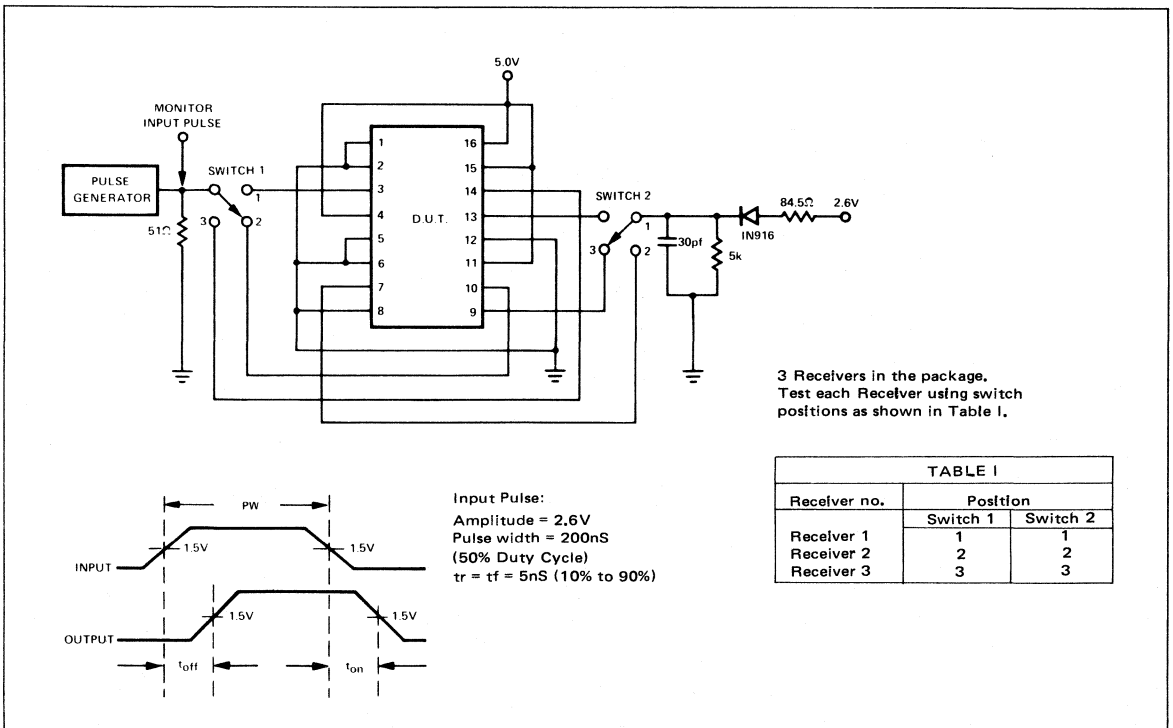
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings
- Manufacturer reserves the right to make design and process changes and improvements.
- Output source current is applied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- $V_{CC} = 0.00V$
- Not more than one output should be shorted at a time.
- Hysteresis is defined as the voltage difference between the R input level at which the output begins to go from "0" to "1" state and the level at which the output begins to go from "1" to "0".
- See Hysteresis test circuit.
- Refer to AC test circuits.
- $V_{CC} = 5.25V$

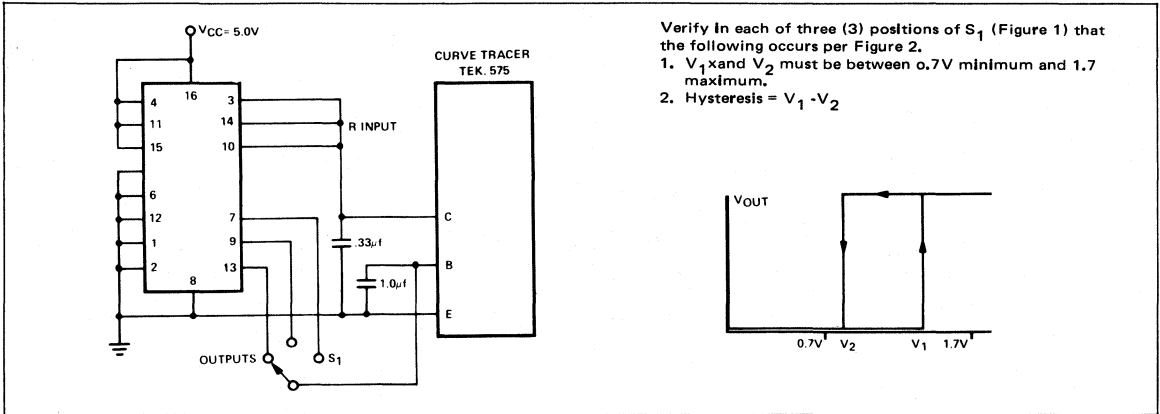
CIRCUIT SCHEMATIC



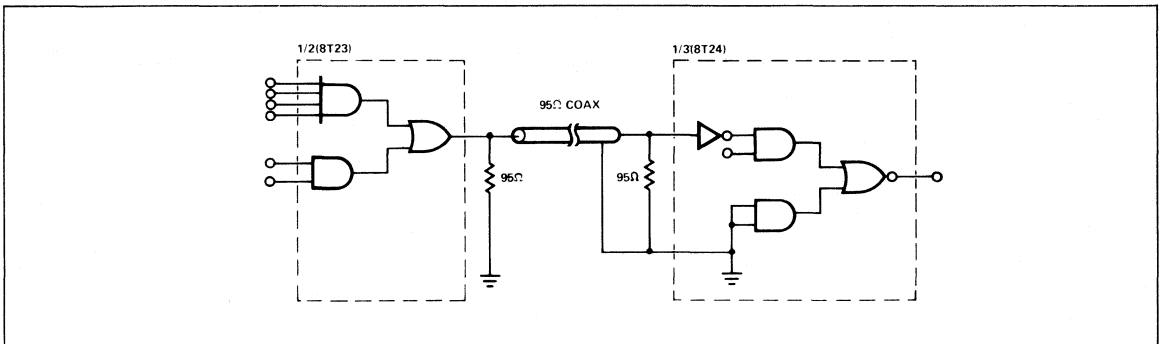
AC TEST CIRCUIT AND WAVEFORMS



HYSTERESIS TEST CIRCUIT



TYPICAL APPLICATION



0°C TO +75°C

DIGITAL 8T SERIES INTERFACE TTL/MSI

## DESCRIPTION

The 8T25 is a Dual MOS-to-TTL interface element. The Sense Amplifier is designed to accept low level MOS signals from the output of Random Access Memories and the information is stored in a latch in response to an external Strobe signal. A tristate output buffer presents the data to the output using conventional TTL logic levels. The 8T25 operates from a single +5 volt supply.

## CIRCUIT OPERATION

A logic "1" level on the PRESET/DISABLE line will disconnect the outputs of the Sense Amplifier from a common bus by turning both totem-pole transistors off. When the Preset/Disable line returns to a logic "0" level, the outputs will be preset to a logic "1" state. A low-going Strobe pulse will then transfer the data at Inputs A and B to their respective outputs non-inverted.

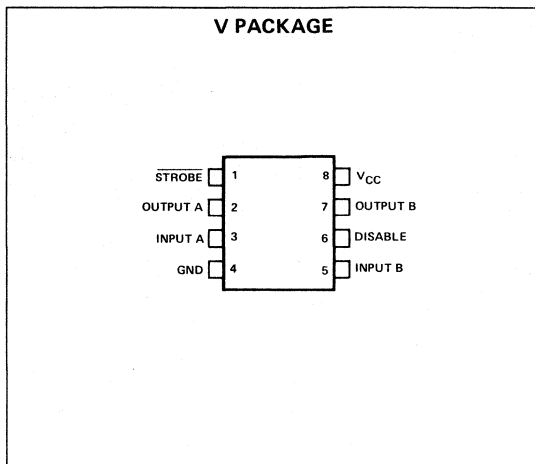
Due to the internal latch, output data will remain stable regardless of any change in input levels until a Disable signal again forces both outputs to the high impedance state.

If the STROBE is not used (STROBE = 0) the effect of the Preset/Disable line is to first disconnect the data from the tri-state bus (PRESET/DISABLE HIGH) and then transfer the input data to the output.

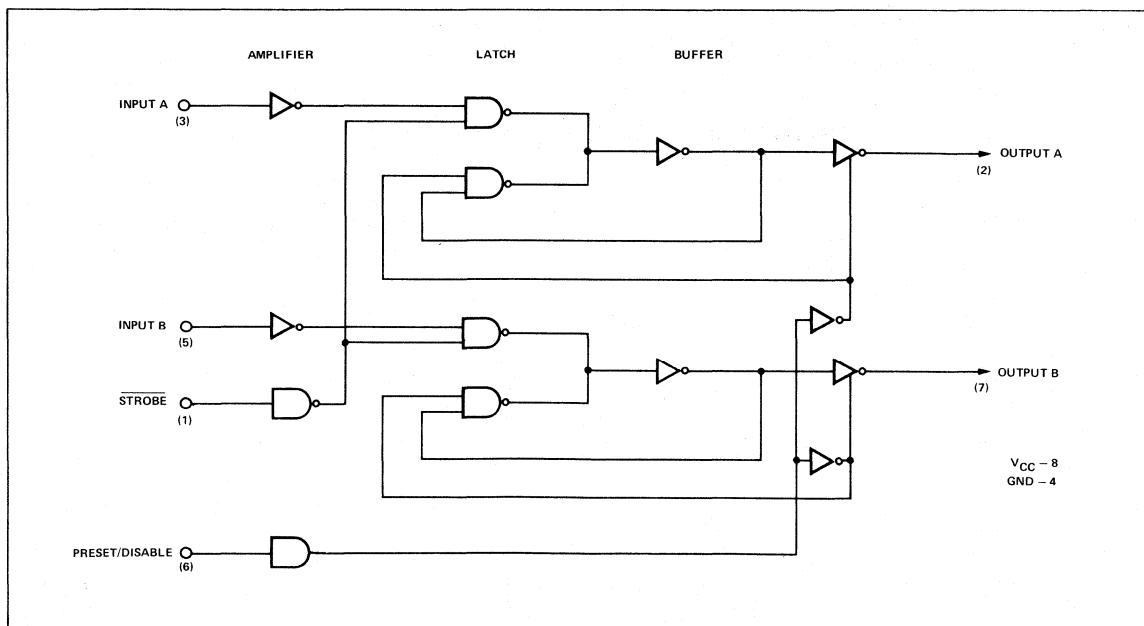
## FEATURES

- MOS-TO-TTL CONVERTER
- INTERNAL LATCH
- TRISTATE OUTPUTS
- SINGLE +5V SUPPLY

## PIN CONFIGURATION (Top View)



## LOGIC DIAGRAM



**ELECTRICAL CHARACTERISTICS**  $T_A = 0^\circ\text{C TO } 75^\circ\text{C}$ ,  $V_{CC} = 5\text{V} \pm 5\%$

PARAMETER	LIMITS				INPUTS					
	MIN.	TYP.	MAX.	UNITS	A	B	DISABLE	STROBE	OUTPUTS	NOTES
"1" Output Voltage	2.8	3.5		V	400 $\mu$ A	400 $\mu$ A	0.8V	0.8V	-1.5mA	7
"0" Output Voltage			0.40	V	200 $\mu$ A	200 $\mu$ A	0.8V	0.8V	16mA	8
Output "1" Leakage Current			100	$\mu$ A	200 $\mu$ A	1.5mA	2.0V	0.8V	3.9V	
Output "A" Leakage Current			100	$\mu$ A	1.5mA	200 $\mu$ A	2.0V	0.8V	3.9V	
Output "0" Leakage Current			100	$\mu$ A	1.5mA	1.5mA	2.0V	0.8V	OV	
Input Clamp Voltage			-1.5	V			-12mA	-12mA		
Power/Current Consumption			210/40	mW/mA	400 $\mu$ A	400 $\mu$ A	4.5V	OV		11
"0" Input Current (Strobe, Preset/Disable)	-0.1		-1.6	mA			OV	OV		
"1" Input Current (Strobe, Disable)			40	$\mu$ A			4.5V	4.5V		
Input Voltage Rating (Strobe, Preset/Disable)			5.5	V			1.0mA	1.0mA		
Output Short Circuit Current	-20		-70	mA				2.0V	OV	10, 11

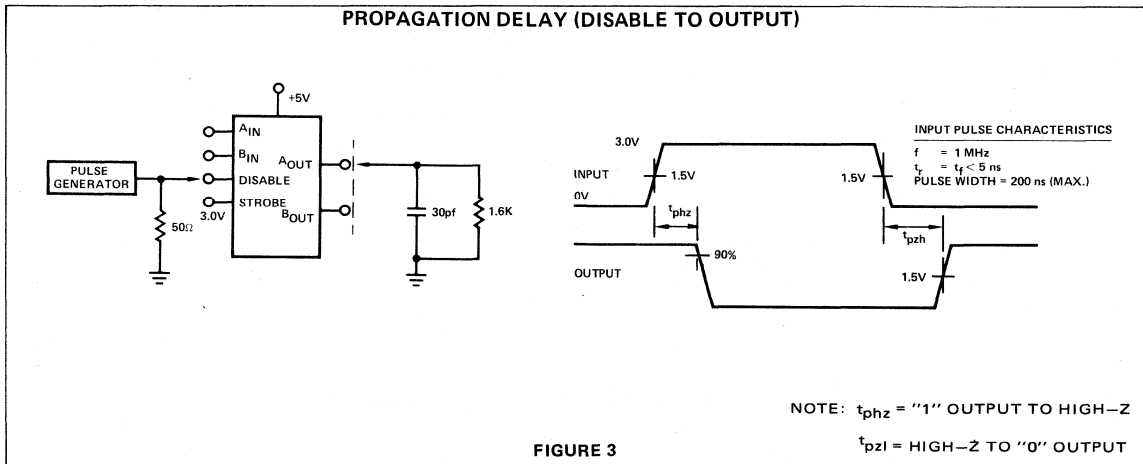
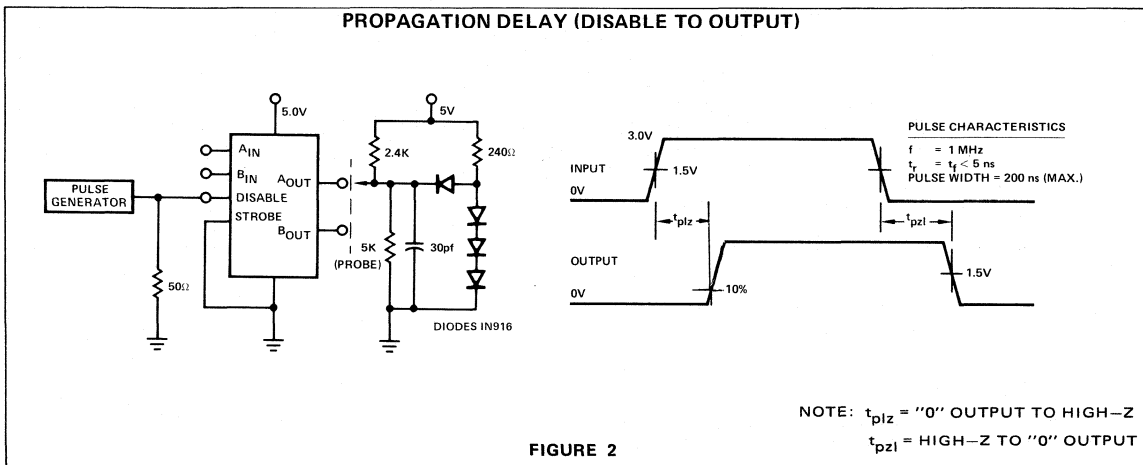
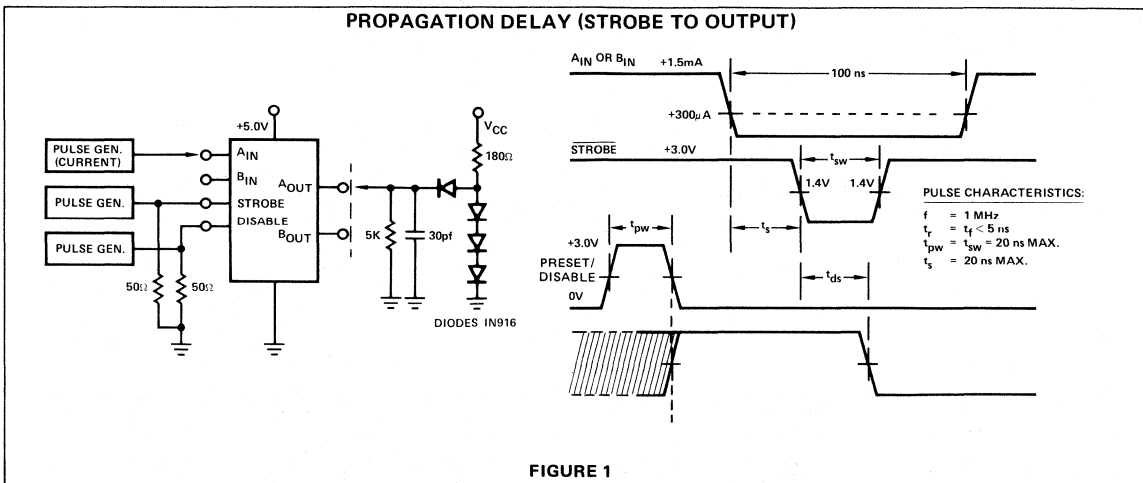
**NOTES**

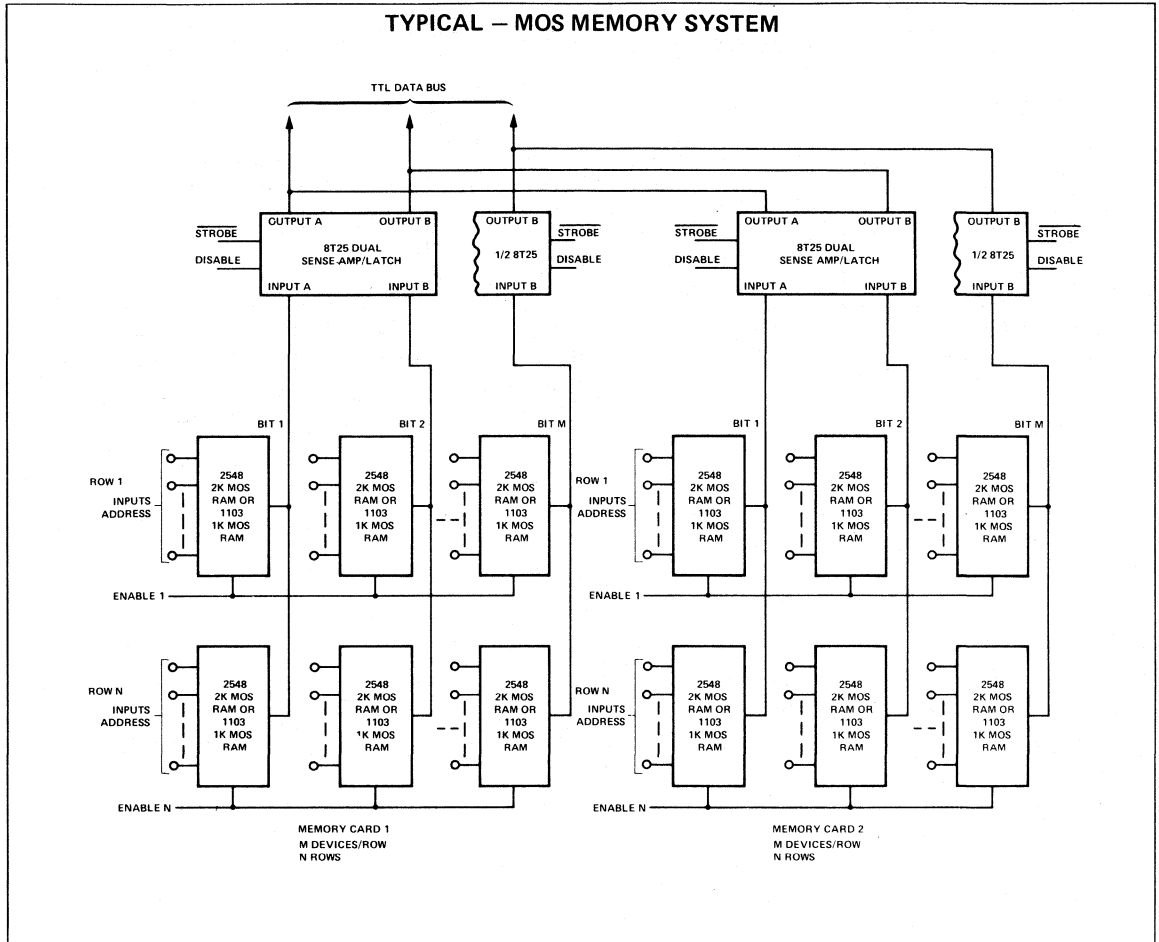
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figure.
- Not more than one output should be shorted at a time.
- $V_{CC}=5.25\text{V}$ .

**ELECTRICAL CHARACTERISTICS**  $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V}$

PARAMETER	LIMITS				INPUTS					
	MIN.	TYP.	MAX.	UNITS	A	B	DISABLE	STROBE	OUTPUTS	NOTES
Propagation Delay Strobe to Output ( $t_{ds}$ )		15	25	ns						Fig. 1
Disable to "0" Output ( $t_{pZL}$ )		15	25	ns						Fig. 2
"0" Output to Disable ( $t_{pLZ}$ )		8	15	ns						Fig. 2
Disable to "1" Output ( $t_{pZH}$ )		15	25	ns						Fig. 3
"1" Output to Disable ( $t_{pHZ}$ )		9	20	ns						Fig. 3

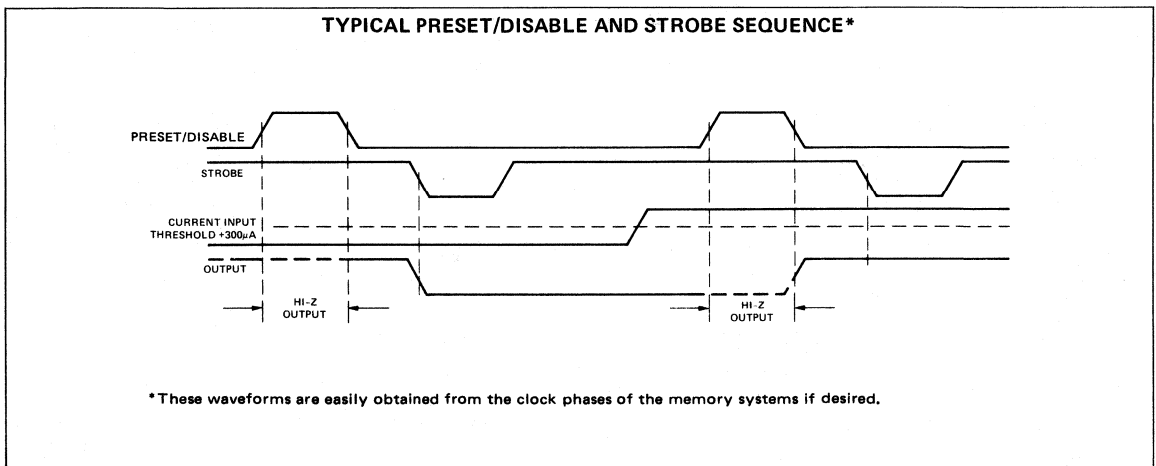
AC TEST CIRCUITS AND WAVEFORMS





NOTE: EACH MEMORY CARD IS AN  
 N (2K) XM MEMORY FOR 2548 2K MOS RAM  
 N(K) XM MEMORY FOR 1103 1K MOS RAM

### TYPICAL WAVEFORMS





### DESCRIPTION

The 8T26 consists of four pairs of tri-state logic elements configured as Quad Bus Drivers/Receivers along with separate buffered receiver enable and driver enable lines. This single IC Quad Transceiver design distinguishes the 8T26 from conventional multi-IC implementations. In addition, the 8T26's ultra high speed while driving heavy bus capacitance (300 pF) makes the device particularly suitable for memory systems and bidirectional data busses.

Both the Driver and Receiver gates have tri-state outputs and low-current PNP inputs. Tri-state outputs provide the high switching speeds of totem-pole TTL circuits while offering the bus capability of open collector gates. PNP inputs reduce input loading to 200µA maximum.

A logic "1" on the Data Enable (D/E) input allows input data to be transferred to the outputs of the Drivers while a logic "0" will force the outputs to a high impedance state and will also disable the PNP resulting in negligible input load current. The Driver gate will sink 40mA of current with a maximum  $V_{CE}$  of 0.5V.

The Receiver gates are enabled by a logic "0" on the Receiver Enable (R/E) pin and provide 16mA current sink capability. A logic "1" forces the Receiver outputs to a high impedance state and disables the PNP inputs.

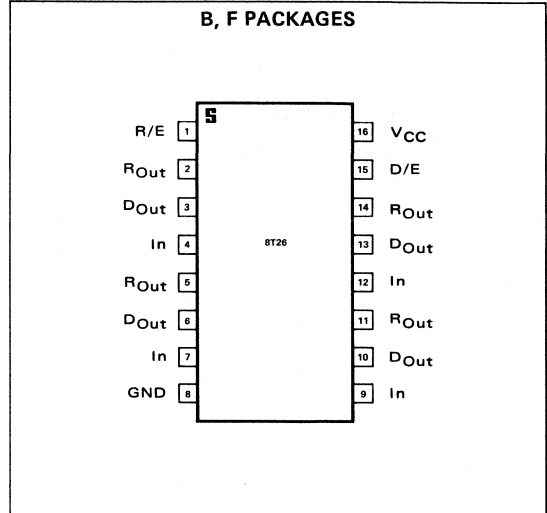
### FEATURES

- SCHOTTKY-CLAMPED TTL
- TRI-STATE OUTPUTS (40 mA CURRENT SINK)
- LOW CURRENT PNP INPUTS
- SCHOTTKY INPUT CLAMP DIODES
- HIGH SPEED (20 ns WITH 300 pF LOAD)

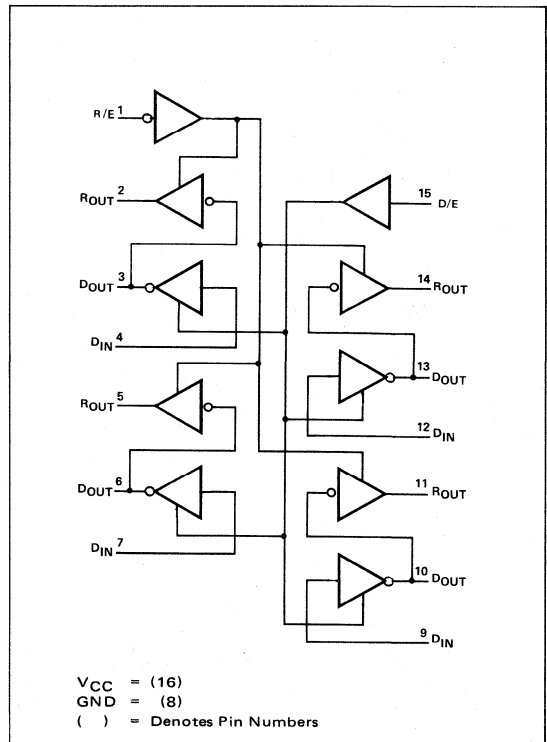
### APPLICATIONS

- HALF-DUPLEX DATA TRANSMISSION
- MEMORY INTERFACE BUFFERS
- DATA ROUTING IN BUS-ORIENTED SYSTEMS
- HIGH CURRENT DRIVERS
- MOS/CMOS-TO-TTL INTERFACE

### PIN CONFIGURATION (Top View)



### LOGIC DIAGRAM



**SIGNETICS TRI-STATE QUAD BUS TRANSCEIVER ■ 8T26**
**ELECTRICAL CHARACTERISTICS  $V_{CC} = 5.0V \pm 5\%$ ,  $T_A = -0^\circ C$  TO  $+75^\circ C$** 

PARAMETER	MIN.	TYP.	MAX.	UNITS	CONDITION	NOTES
Input "0" current (All inputs)			-200	$\mu A$	$V_{in} = 0.4$	
Input "1" current $D_{in}, D_E, R_E$			25	$\mu A$	$V_{in} = 5.25$	
Input (0) Threshold Voltage	0.85			volts		
Input (1) Threshold Voltage			2	volts		
$D_{Out}$ (1) Voltage Pins 3,6,10,13	2.6	3.1		volts	$I_{out} = -10mA$	7
$R_{Out}$ (1) Voltage Pins 2,5,11,14	2.6	3.1		volts	$I_{out} = -2.0mA$	7
$D_{Out}$ (0) Voltage Pins 3,6,10,13			0.50	volts	$I_{out} = 40mA$	8
$R_{Out}$ (0) Voltage Pins 2,5,11,14			0.50	volts	$I_{out} = 16mA$	8
Output (1) off leakage current			100	$\mu A$	$V_{out} = 2.6V$	
Input clamp voltage			-1.0	volts	$I_{in} = -5mA$	
$D_{Out}$ short circuit current – Pins 3,6,10,13	-50		-150	mA	$V_o = 0$ volts	11, 12
$R_{Out}$ short circuit current – Pins 2,5,11,14	-30		-75	mA	$V_o = 0$ volts	11, 12
Power/Current Consumption			457/87	mW/mA	$V_{cc} = 5.25$	11

**ELECTRICAL CHARACTERISTICS  $V_{CC} = 5.00V$ ,  $T_A = 25^\circ C$** 

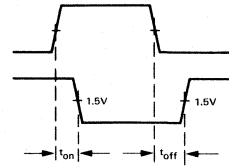
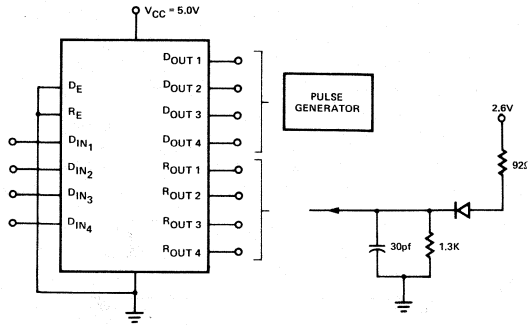
PARAMETER	MIN.	TYP.	MAX.	UNITS	CONDITION	NOTES
Propagation Delay						
$D_{Out}$ to $R_{Out}$ ( $t_{on}$ )		6	10	nsec	$C_L = 30pF$	9
$D_{Out}$ to $R_{Out}$ ( $t_{off}$ )		13	18	nsec	$C_L = 30pF$	9
$D_{In}$ to $D_{Out}$ ( $t_{on}$ )		16	20	nsec	$C_L = 300pF$	9
$D_{In}$ to $D_{Out}$ ( $t_{off}$ )		16	20	nsec	$C_L = 300pF$	9
Data Enable to Data Output						
High Z to 0 ( $t_{pZL}$ )		29	38	nsec	$C_L = 300pF$	9
0 to High Z ( $t_{pLZ}$ )		35	43	nsec	$C_L = 300pF$	9
Receiver Enable to Receiver Output						
High Z to 0 ( $t_{pZL}$ )		20	30	nsec	$C_L = 30pF$	9
0 to High Z ( $t_{pLZ}$ )		10	17	nsec	$C_L = 30pF$	9

**NOTES**

- All voltage measurements are referenced to the ground terminal.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition:  
"UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each output and the associated data input independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Circuits.
- Manufacturer reserves the right to make design and process changes and improvements.
- $V_{CC} = 5.25$  volts.
- Do not ground more than one output at a time.

AC TEST CIRCUITS AND WAVEFORMS

PROPAGATION DELAY (D<sub>OUT</sub> TO R<sub>OUT</sub>)



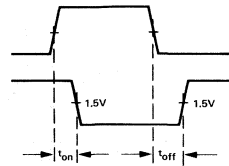
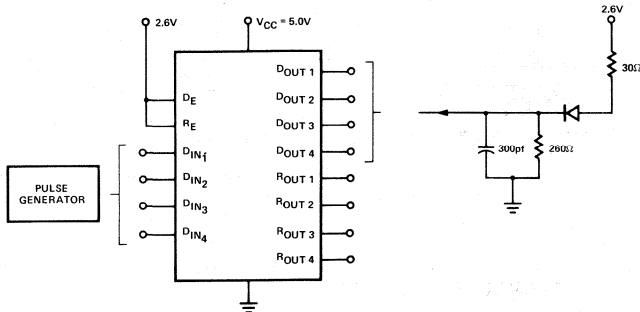
INPUT PULSE:

$t_r = t_f = 5\text{ns}$  (10% to 90%)

freq = 10MHz (50% duty cycle)

Amplitude = 2.6V

PROPAGATION DELAY (D<sub>IN</sub> TO D<sub>OUT</sub>)



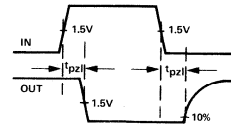
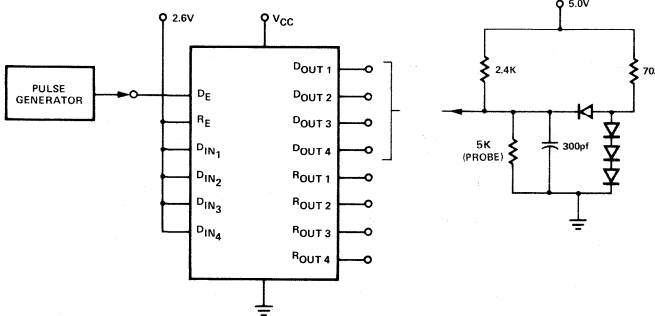
INPUT PULSE:

$t_r = t_f = 5\text{ns}$  (10% to 90%)

freq = 10MHz (50% Duty Cycle)

Amplitude = 2.6V

PROPAGATION DELAY (DATA ENABLE TO DATA OUTPUT)



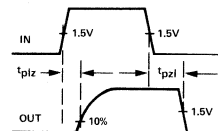
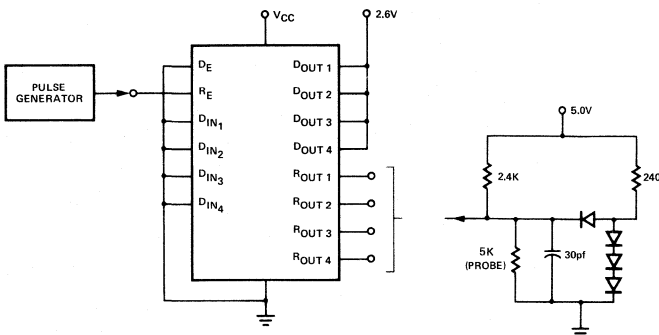
INPUT PULSE:

$t_r = t_f = 5\text{ns}$  (10% to 90%)

freq = 5MHz (50% Duty Cycle)

Amplitude = 2.6V

PROPAGATION DELAY (RECEIVE ENABLE TO RECEIVE OUTPUT)



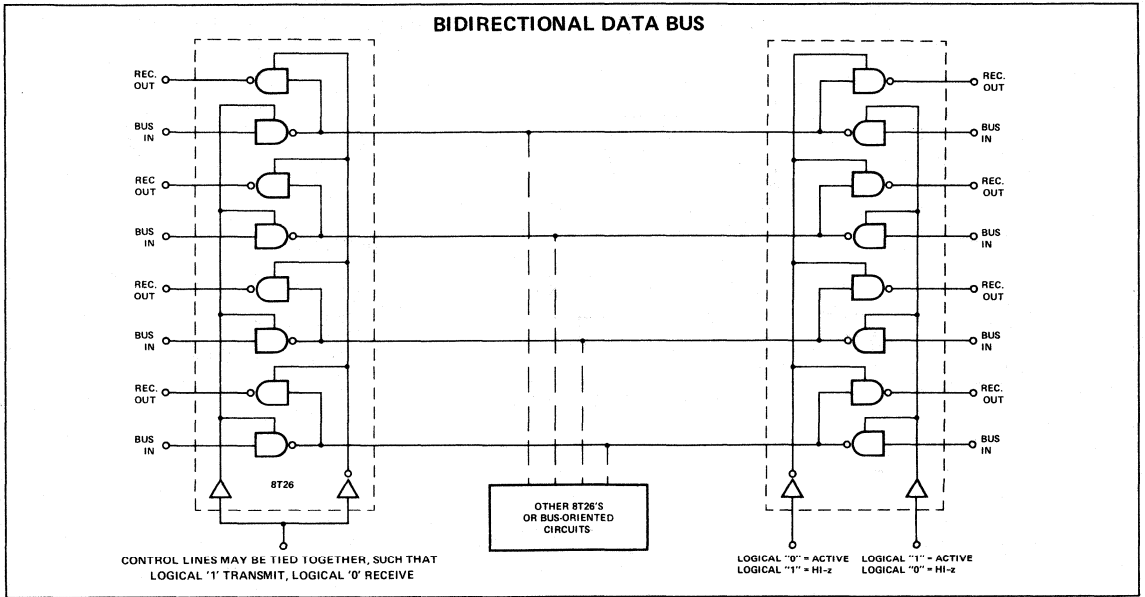
INPUT PULSE:

$t_r = t_f = 5\text{ns}$  (10% to 90%)

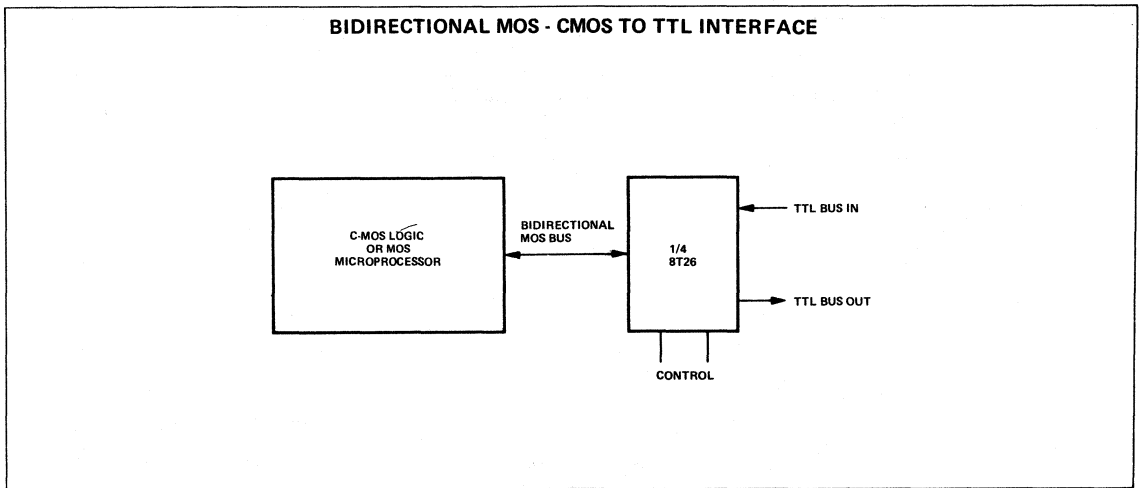
freq = 5MHz (50% Duty Cycle)

Amplitude = 2.6V

TYPICAL APPLICATIONS



BLOCK DIAGRAM



## PRELIMINARY SPECIFICATION

## DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

The 8T30 is a dual bi-directional bus interchange element that interfaces MOS and TTL data busses. Data can be exchanged in a half-duplex transmission mode from a "party line" TTL/DTL bus to a MOS transceiver port and a TTL/DTL transceiver port. For maximum versatility the receive inputs and high current sink open collector transmit outputs are brought out separately.

Common receive and transmit enable controls condition each half of the 8T30 for six valid modes of operation as tabulated in Table 1.

Pins 6 and 4 (8 and 10) are typically connected such that data from a common high performance "party line" bus can be routed to and from the TTL/DTL and MOS transceiver ports. In addition, wrap-around inputs are provided such that TTL/DTL data can be sent directly to the MOS transceiver port and the TTL/DTL "party line drivers" without using the TTL/DTL transceiver port.

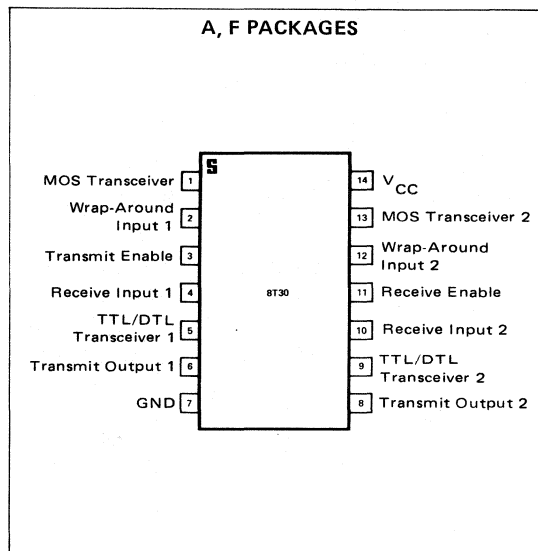
A high performance emitter follower driver and a low current base input on the MOS transceiver port make the 8T30 a superior MOS bus interface element.

A power-down sequence (as  $V_{CC}$  is varied from 5.25V to 0V) of the 8T30 will have no effect on the transmit outputs i.e., the "party line" bus driving the port controller.

### FEATURES

- DUAL TRANSCEIVER DESIGN
- HIGH CURRENT TRANSMIT OUTPUTS (60 mA OPEN COLLECTOR)
- HIGH CURRENT SINK TTL/DTL TRANSCEIVER OUTPUTS (24 mA)
- EMITTER FOLLOWER MOS BUS DRIVE (-1.6 mA AT 4.25V)
- LOW INPUT CURRENT MOS BUS (200  $\mu$ A MAX)
- VERSATILE CONTROL INPUTS
- 6 OPERATING MODES

### PIN CONFIGURATIONS (Top View)



### PIN DESIGNATIONS

#### PIN NUMBER

- 1 Half Duplex MOS Transceiver 1
- 2 TTL Wrap-Around Input 1
- 3 Transmit Enable (Common)
- 4 Receive Data 1
- 5 Half Duplex TTL/DTL Transceiver
- 6 Transmit Data 1 (Open Collector)
- 7 Ground
- 8 Transmit Data 2 (Open Collector)
- 9 Half Duplex TTL/DTL Transceiver 2
- 10 Receive Data 2
- 11 Receive Enable (Common)
- 12 TTL Wrap-Around Input 2
- 13 Half Duplex MOS Transceiver 2
- 14  $V_{CC}$

# SIGNETICS DUAL TTL/DTL TO MOS TRANSCEIVER/PORT CONTROLLER ■ 8T30

**8T30 VALID OPERATING MODES** (X = Don't Care, 1 = Logic "1", 0 = Logic "0")

MODE OF OPERATION	PIN FUNCTIONS	PIN NUMBERS					
		6 & 4 (8 & 10)	2 (12)	5 (9)	3	11	1 (13)
Port Controller Receives Data From TTL/DTL System	Control		0		1	0	
	Data In	Data					Data
	Data Out			Data			
TTL/DTL Transceiver Sends Data to TTL/DTL System	Control		0		0	1	1
	Data In			Data			
	Data Out	Data					
MOS Transceiver Sends Data to TTL/DTL System	Control		0	1	0	1	
	Data In						Data
	Data Out	Data					
MOS Transceiver Receives Data From TTL/DTL Wrap-Around Input	Control	X		1	1	1	
	Data In		Data				
	Data Out						Data
TTL/DTL System Receives Data From TTL/DTL Wrap-Around Input	Control			1	0	1	
	Data In		Data				
	Data Out	Data					Data
Port Controller Idle (Random Activity on Pins 1(13), 2(12), and 5(9) Does Not Affect Bus on 6, 4 (8, 10))	Control		X	X	1	1	X
	Data In	X					
	Data Out	X					

## DC ELECTRICAL CHARACTERISTICS $T_A = 25^\circ\text{C}$ , $V_{CC} = 5.0\text{V}$

CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Propagation Delays						
TTL/DTL Transceiver Inputs to Transmit Outputs	$t_{on}$	14	25	ns	Fig. 1, 2 $R_L = 220\Omega$ , $C_L = 50\text{ pF}$	9
	$t_{off}$	14	20	ns		
MOS Transceiver Inputs to Transmit Outputs	$t_{on}$	23	70	ns	Fig. 2, 3 $R_L = 220\Omega$ , $C_L = 50\text{ pF}$	
	$t_{off}$	23	50	ns		
TTL Wraparound Inputs to Transmit Outputs	$t_{on}$	120	175	ns	Fig. 2, 4 $R_L = 220\Omega$ , $C_L = 50\text{ pF}$ $R_F = 11.2\text{K}$ , $C_F = 30\text{ pF}$	
	$t_{off}$	36	75	ns		
Receive Inputs to TTL/DTL Transceiver Outputs	$t_{on}$	42	60	ns	Fig. 2, 5 $R_L = 100\Omega$ , $C_L = 30\text{ pF}$ Fig. 2, 5 $R_L = 4\text{K}\Omega$ , $C_L = 30\text{ pF}$	
	$t_{off}$	13	20	ns		
Receive Inputs to MOS Transceiver Outputs	$t_{on}$	14	35	ns	Fig. 6, 7 $R_F = 11.2\text{K}$ , $C_F = 30\text{ pF}$	
	$t_{off}$	106	135	ns		
Transmit Enable to Transmit Outputs	$t_{on}$	19	40	ns	Fig. 8, 9 $R_L = 220\Omega$ , $C_L = 50\text{ pF}$	
	$t_{off}$	19	40	ns		
Receive Enable to TTL/DTL Transceiver Outputs	$t_{on}$	46	60	ns	Fig. 9, 10 $R_L = 400\Omega$ , $C_L = 30\text{ pF}$ Fig. 9, 10 $R_L = 4\text{K}\Omega$ , $C_L = 30\text{ pF}$	
	$t_{off}$	19	35	ns		
Receive Enable to MOS Transceiver Outputs	$t_{on}$	20	50	ns	Fig. 11, 12 $R_F = 11.2\text{K}$ , $C_F = 30\text{ pF}$	
	$t_{off}$	115	155	ns		

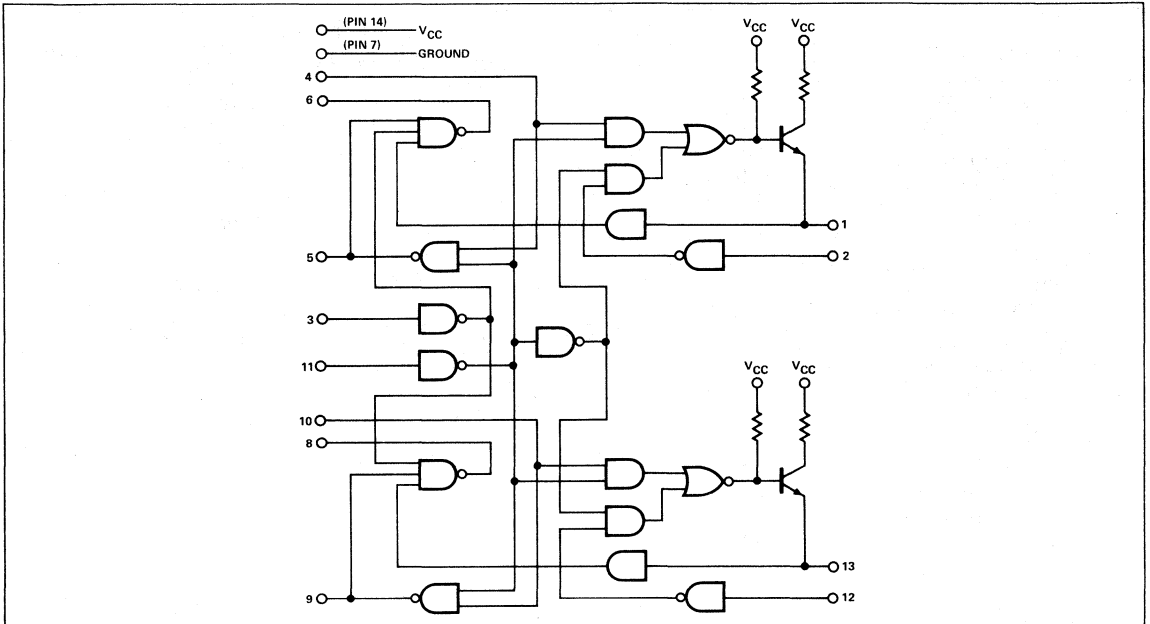
## AC ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS		NOTES
	MIN.	TYP.	MAX.	UNITS	OUTPUTS	INPUTS	
"1" Output Voltage (TTL/DTL Transceiver)			3.0	V	-150 $\mu$ A	0.8V, 2.0V	6
"1" Output Voltage (MOS Transceiver)			4.25	V	-1.6mA	0.8V, 2.0V	6, 8
"1" Output Leakage Current (Transmit Outputs)			250	$\mu$ A	$V_{CC}$	0.8V, 2.0V	
"0" Output Voltage (Transmit Outputs)			0.4	V	60mA	0.8V, 2.0V	7
"0" Output Voltage (TTL/DTL Transceiver)			0.4	V	25mA	0.8V, 2.0V	7
"0" Output Voltage (MOS Transceivers)	-1.2		0.4	V	-1mA	0.8V, 2.0V	
"1" Input Current (Enable and Wrap-around Inputs)			40	$\mu$ A		2.4V	
"1" Input Current (Receive Inputs)			80	$\mu$ A		2.4V	
"1" Input Current (MOS Transceivers)			200	$\mu$ A		5.25V	
"0" Input Current (Enable and Wrap-around Inputs)			-1.6	mA		0.4V	
"0" Input Current (TTL/DTL Transceiver and Receive Inputs)			-3.2	mA		0.4V	
"0" Input Current (MOS Transceiver)			-0.5	mA		0.4V	
Power/Current Consumption			370 70	mW mA		REC. ENABLE = 0V	8

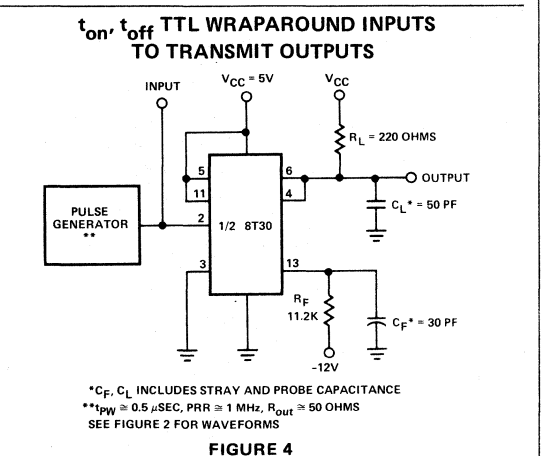
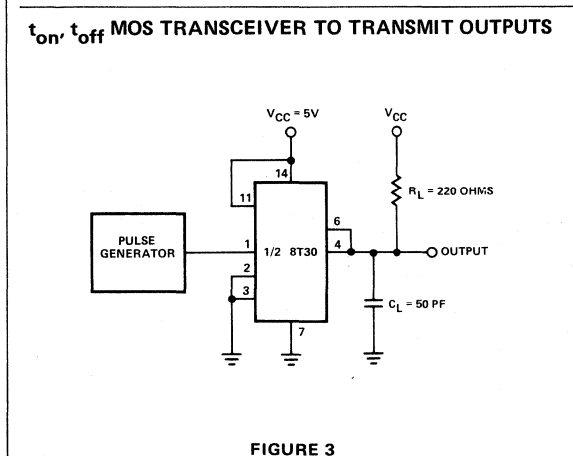
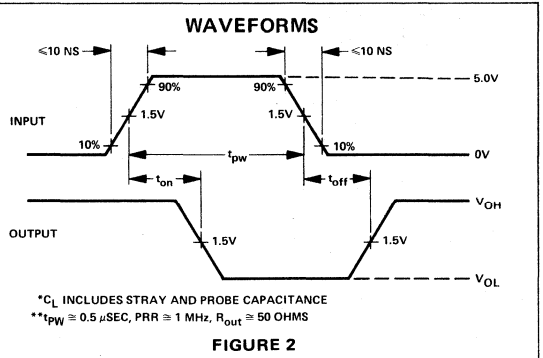
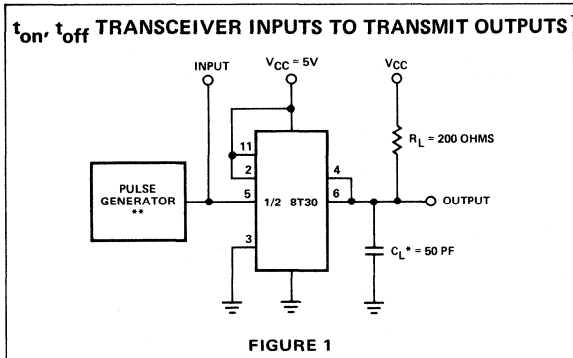
## NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with the ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition "Up" = "1" level, "Down" = "0" level
- Precautionary measures should be taken to assure current limiting in accordance with absolute maximum ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- $V_{CC} = 5.25V$
- See AC test figures and waveforms.

LOGIC DIAGRAM



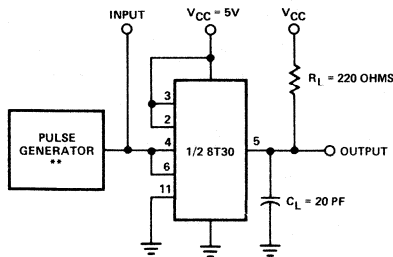
AC TEST FIGURES AND WAVEFORMS





AC TEST FIGURES AND WAVEFORMS (cont'd)

$t_{on}$ ,  $t_{off}$  RECEIVE INPUTS TO TTL/DTL TRANSCEIVER OUTPUTS



\* $C_L$  INCLUDES STRAY AND PROBE CAPACITANCE  
 \*\* $t_{pw} \cong 0.5 \mu\text{SEC}$ ,  $\text{PRR} \cong 1 \text{ MHz}$ ,  $R_{out} \cong 50 \text{ OHMS}$   
 SEE FIGURE 2 FOR WAVEFORMS

FIGURE 5

$t_{on}$ ,  $t_{off}$  RECEIVE INPUTS TO MOS TRANSCEIVER OUTPUTS

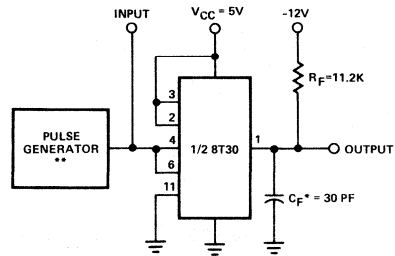
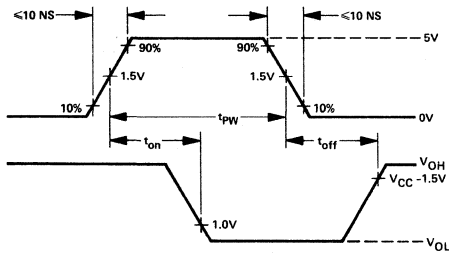


FIGURE 6

$t_{on}$ ,  $t_{off}$  WAVEFORMS



\* $C_L$  INCLUDES STRAY AND PROBE CAPACITANCE  
 \*\* $t_{pw} \cong 0.5 \mu\text{SEC}$ ,  $\text{PRR} \cong 1 \text{ MHz}$ ,  $R_{out} \cong 50 \text{ OHMS}$

FIGURE 7

TRANSMIT ENABLE TO TRANSMIT OUTPUTS

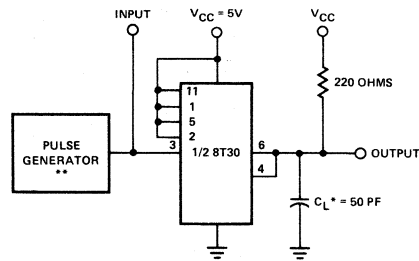
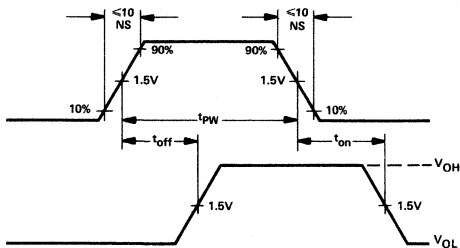


FIGURE 8

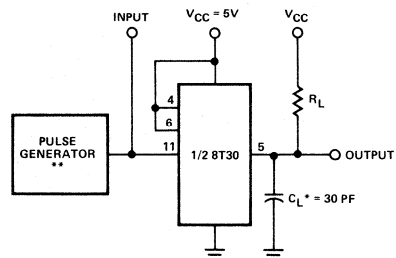
$t_{on}$ ,  $t_{off}$  WAVEFORMS



\* $C_F$ ,  $C_L$  INCLUDES STRAY AND PROBE CAPACITANCE  
 \*\* $t_{pw} \cong 0.5 \mu\text{SEC}$ ,  $\text{PRR} \cong 1 \text{ MHz}$ ,  $R_{out} \cong 50 \text{ OHMS}$

FIGURE 9

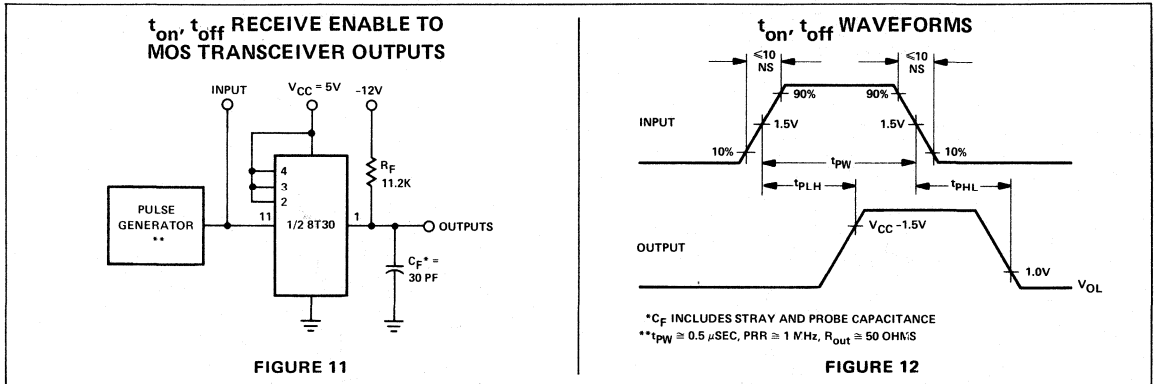
$t_{on}$ ,  $t_{off}$  RECEIVE ENABLE TO TTL/DTL TRANSCEIVER OUTPUTS



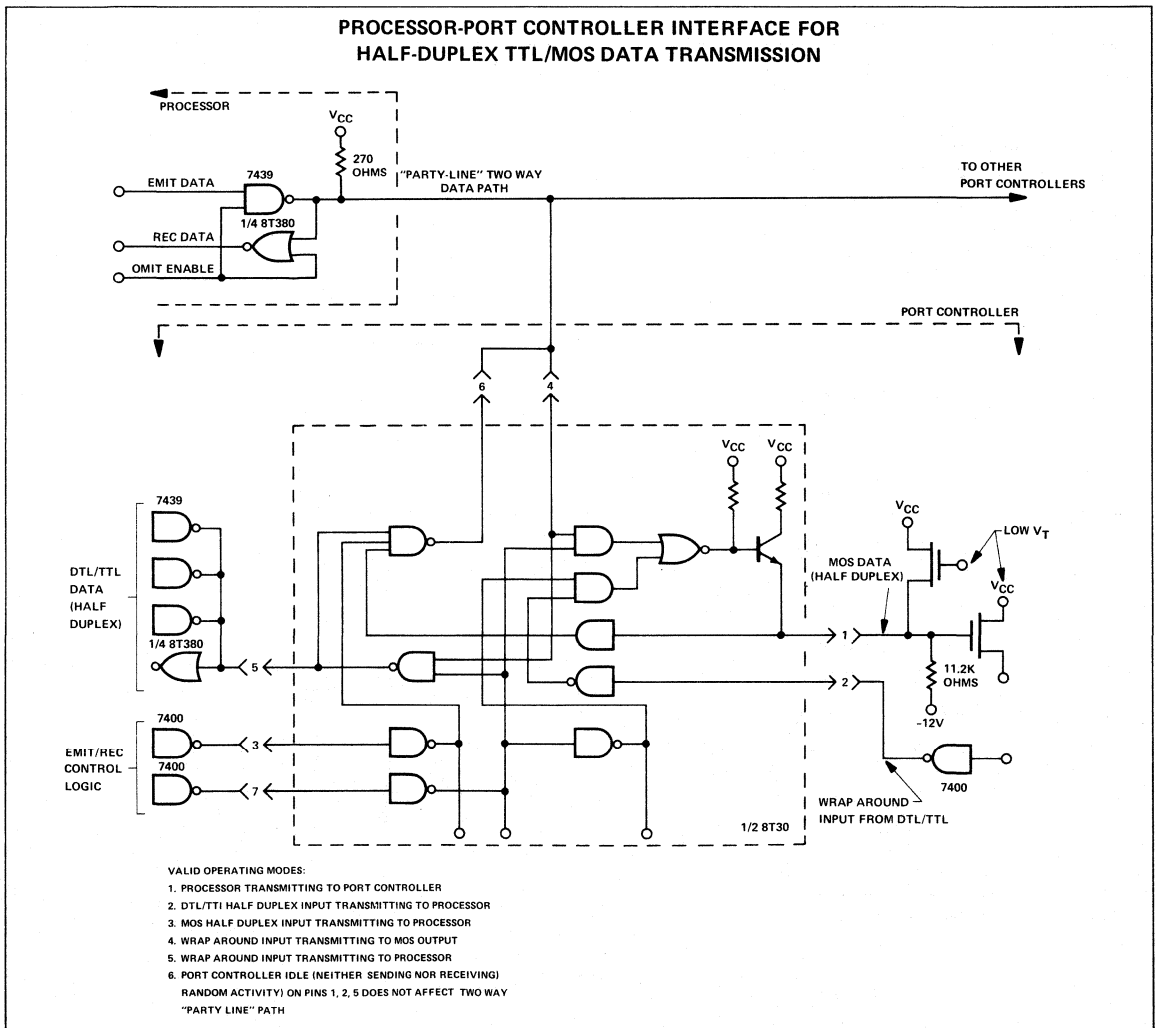
\* $C_F$ ,  $C_L$  INCLUDES STRAY AND PROBE CAPACITANCE  
 \*\* $t_{pw} \cong 0.5 \mu\text{SEC}$ ,  $\text{PRR} \cong 1 \text{ MHz}$ ,  $R_{out} \cong 50 \text{ OHMS}$   
 SEE FIGURE 2 FOR WAVEFORMS

FIGURE 10

AC TEST FIGURES AND WAVEFORMS



TYPICAL APPLICATION



## PRELIMINARY SPECIFICATION

## DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

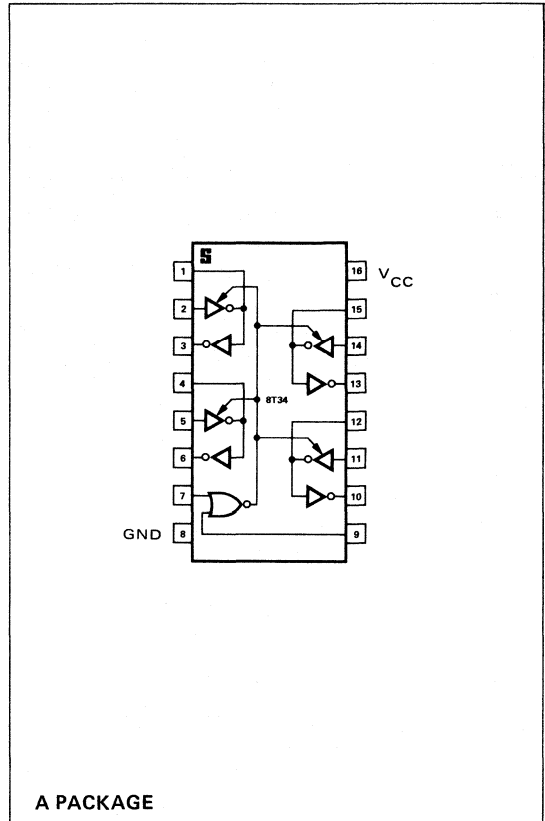
The 8T34 is a quad transceiver with a common two input driver disable control. Tri-state driver outputs together with low input current requirements for the receivers offer extreme versatility in bus organized data transmission systems. The data busses may be terminated or unterminated.

Drivers in the third output state (Hi-Z) load the bus only with negligible current. The receiver input current is low, allowing at least 100 driver/receiver pairs to utilize a single bus. The receiver incorporates hysteresis to provide maximum noise immunity. In addition the receiver does not load the bus with  $V_{CC} = 0V$  as it may be the case when peripherals drive a common I/O bus and are shut off.

### FEATURES

- RECEIVER HYSTERESIS (TYP. 450 mV)
- RECEIVER NOISE IMMUNITY (TYP. 1.4V)
- RECEIVER INPUT CURRENT (50  $\mu A$  MAX.)  
(FOR NORMAL  $V_{CC}$  AND  $V_{CC} = 0V$ )
- RECEIVER
  - SINK 16 mA at 0.4V
  - SOURCE 5.2 mA at 2.4V
- DRIVER
  - SINK 50 mA at 0.5V
  - SOURCE 10.4 mA at 2.4V
- DRIVERS HAVE TRI-STATE OUTPUTS
- DRIVES 100 $\Omega$  TERMINATED BUSES
- 7400 SERIES COMPATIBLE
- PIN COMPATIBLE WITH DM8834

### PIN CONFIGURATION (Top View)



DIGITAL 8T SERIES INTERFACE TTL/MSI

## DESCRIPTION

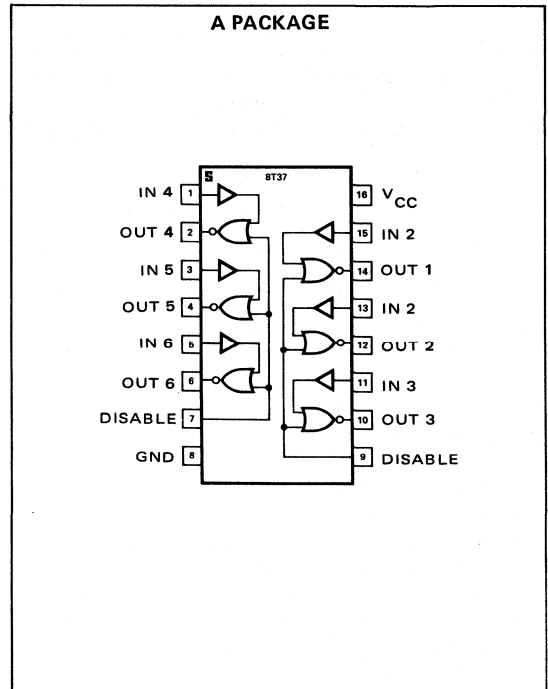
The 8T37 is a hex bus receiver with hysteresis organized as two triple receivers with separate disable lines for each group. Typically the devices may be used in bus organized data transmission systems interconnected by terminated lines. The low input current requirement allows several drivers and receivers to communicate over a common bus in "party line" fashion. A power-up or power-down sequence of the receiver will not affect the bus. Built in hysteresis provides maximum noise immunity and makes the 8T37 also an ideal Schmitt trigger in those applications where the non-linear input characteristics of standard TTL are undesirable.

Low input current requirements make the hex-inverter inputs compatible with MOS/CMOS in addition to DTL/TTL. All inputs have clamping diodes to simplify systems design. The receiver outputs as well as the disable inputs are TTL/DTL compatible.

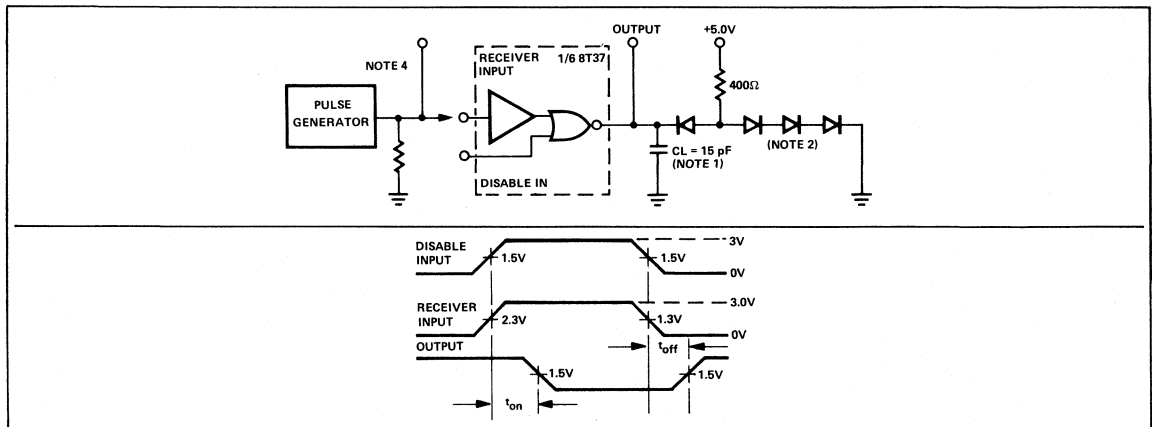
## FEATURES

- HIGH SPEED
- LOW INPUT CURRENT (TYP. 15  $\mu$ A)
- BUILT-IN HYSTERESIS (TYP. 1V)
- HIGH NOISE IMMUNITY (TYP. 2V)
- TEMPERATURE INSENSITIVE THRESHOLDS
- TTL/DTL AND MOS/CMOS COMPATIBLE
- INPUT CLAMP DIODES
- PIN COMPATIBLE WITH DM8838

## PIN CONFIGURATION



## AC TEST FIGURE AND WAVEFORMS



### NOTES

1. Including probe and jig capacitance
2. All diodes are 1N3064
3. Pulse generator characteristics P.A. = 3.5V  
 $Z_{OUT} = 50\Omega$

$$P_{RR} = 1\text{MHz}$$

$$t_r = t_f \leq 10\text{ ns (10% to 90%)}$$

$$\text{Duty Cycle} = 50\%$$

4. When testing receiver, Disable = 0; when testing disable, Receiver = 0.

# SIGNETICS HEX BUS RECEIVER WITH HYSTERESIS-SCHMITT TRIGGER ■ 8T37

## DC ELECTRICAL CHARACTERISTICS Over Recommended Operational Temperature and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS			NOTES
	MIN	TYP	MAX	UNITS	RECEIVER INPUT	DISABLE INPUT	OUTPUT	
"1" Output Voltage	2.4			V	0.5V	0.8V	-400 $\mu$ A	6
"0" Output Voltage			0.4	V	4.0V	0.8V	16mA	7
Maximum Receiver Input Current		15	50	$\mu$ A	4.0V			8
		1	50	$\mu$ A	4.0V			9
High Level Receiver Threshold	1.80	2.25	2.50	V		0.8V	16mA	7
Low Level Receiver Threshold	1.05	1.30	1.55	V		0.8V	-400 $\mu$ A	6
"1" Input Current Disable Input			80	$\mu$ A		2.4V		
"0" Input Current Disable Input			-3.2	mA	4V	0.4V		
Input Clamp Voltage (all)		-1.0	-1.5	V	12mA	12mA		
Output Short Circuit Current	-18		-55	mA	0.5V	0V	0V	8; 10
Power Consumption/Supply Current		236/45	315/60	mW/ mA	4V	0V		8

## AC ELECTRICAL CHARACTERISTICS T<sub>A</sub> = 25°C, V<sub>CC</sub> = 5.0V

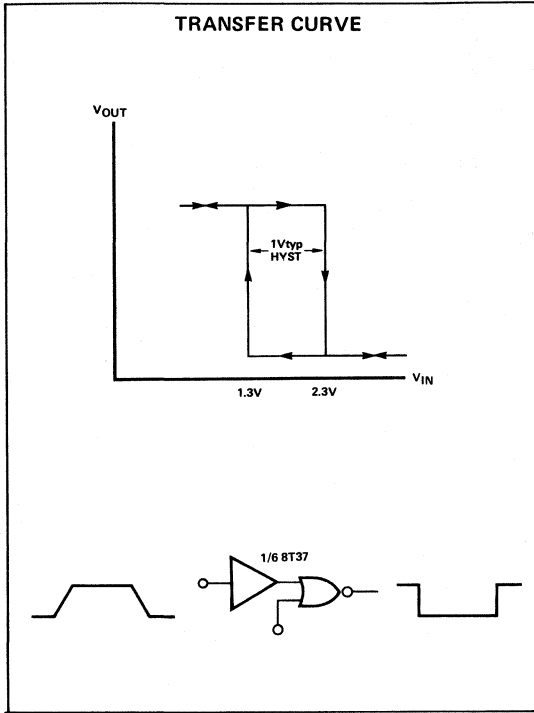
CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Propagation Delays (t <sub>on</sub> , t <sub>off</sub> )						
Receiver t <sub>on</sub>		10	30	ns	R <sub>L</sub> = 400 $\Omega$	11
t <sub>off</sub>		20	30	ns		
Disable t <sub>on</sub>		9	15	ns	C <sub>L</sub> = 15pF	
t <sub>off</sub>		11	15	ns		

### NOTES

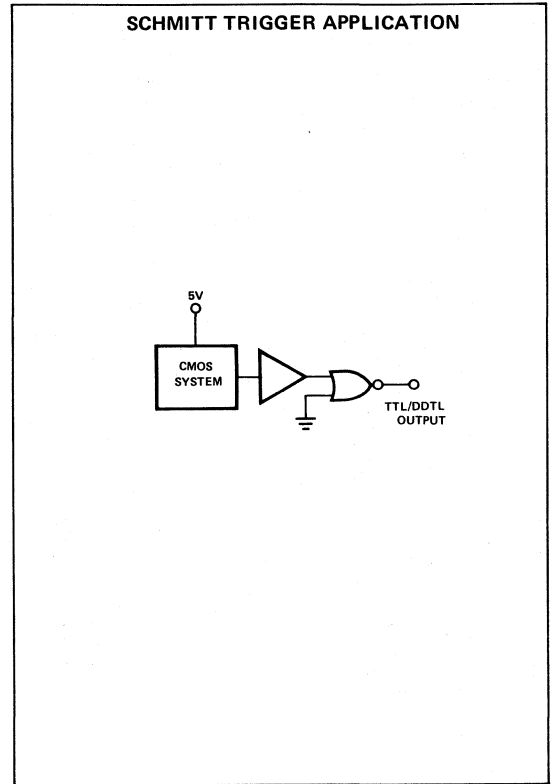
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1" "DOWN" Level "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- V<sub>CC</sub> = 5.25 volts.
- V<sub>CC</sub> = 0 volts.
- Not more than one output should be shorted at a time.
- See AC test figure and waveforms.

**SCHMITT TRIGGER**

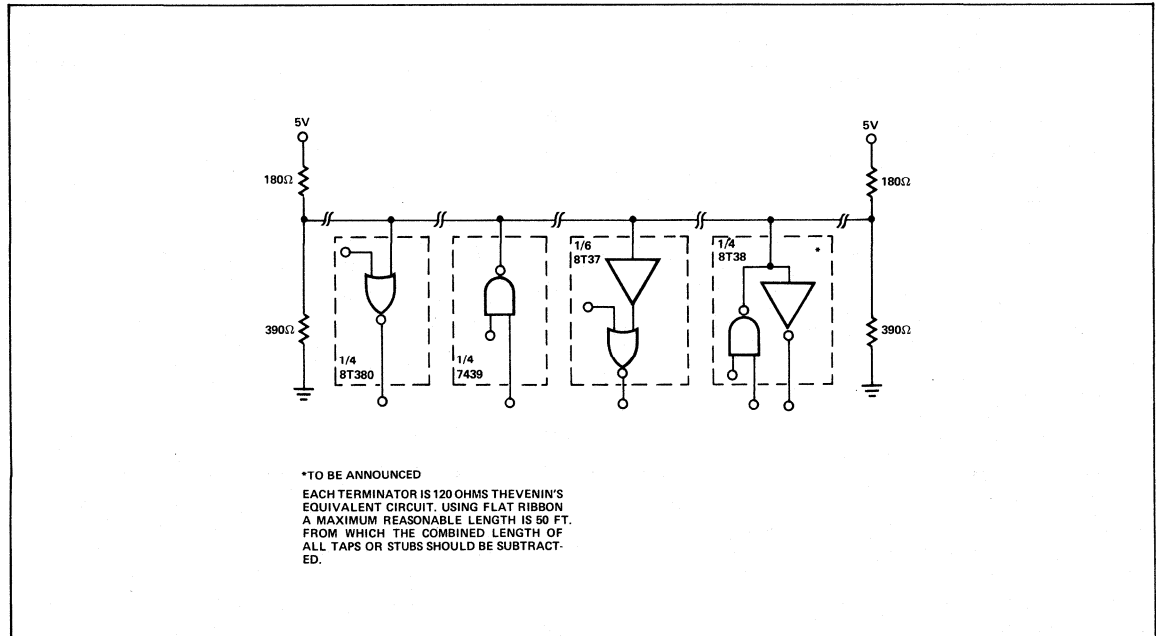
The receiver transfer curve shown makes the 8T37 ideal in a variety of Schmitt Trigger and waveshaping applications.



**C-MOS TO TTL INTERFACE**



**TYPICAL APPLICATION**



## PRELIMINARY INFORMATION

DIGITAL 8T SERIES INTERFACE TTL/MSI

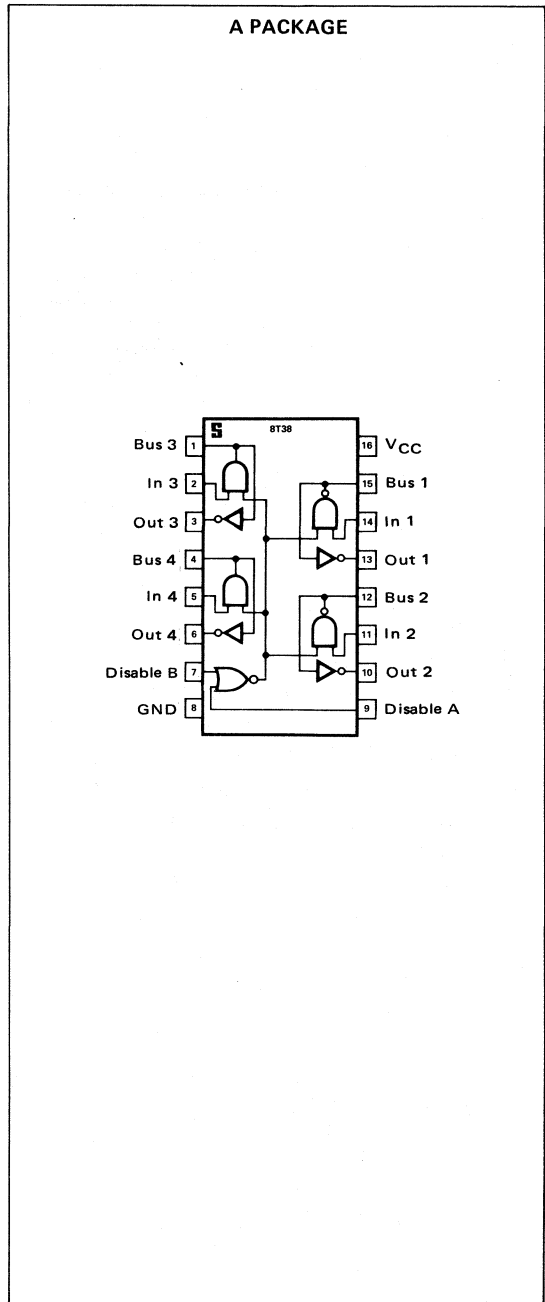
### DESCRIPTION

The 8T38 is a quad bus transceiver with a common two input disable control for the drivers. Open collector driver outputs together with low input requirements for the receivers offer extreme versatility in low cost bus organized systems.

Busses may be terminated at both ends such that up to 100 driver/receiver pairs can utilize a common data bus. The receiver incorporates hysteresis to provide maximum noise immunity. In addition the receiver does not load the bus when  $V_{CC} = 0$ .

In those applications where only bus receivers are required the 8T380 quad bus receiver should be considered.

### PIN CONFIGURATION (Top View)



### FEATURES

- RECEIVER HYSTERESIS (typ. 450mV)
- RECEIVER NOISE IMMUNITY (typ. 1.4V)
- RECEIVER INPUT CURRENT ( $50\mu\text{A}$  max)  
(FOR NORMAL  $V_{CC}$  AND  $V_{CC} = 0\text{V}$ )
- RECEIVER
  - SINK 16mA at 0.4V
  - SOURCE 5.2mA at 2.4V
- DRIVER
  - SINK 50mA at 0.5V
- DRIVERS HAVE OPEN COLLECTOR OUTPUTS
- DRIVES  $100\Omega$  TERMINATED BUSES
- 7400 SERIES COMPATIBLE
- PIN COMPATIBLE WITH DM 8838

### PRELIMINARY SPECIFICATION

DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

The 8T50/8T70 family of seven segment decoder/drivers are designed specifically to drive LED displays and offer either constant current sinking outputs or constant current sourcing outputs. Therefore common anode or common cathode LED's can be accommodated depending on the choice of decoder/driver. The constant current feature overcomes any variation in forward voltage of the LED's and completely eliminates current limiting resistors required with conventional decoder/drivers. The 8T50/70 series devices are designed for DC operated or multi plexed displays.

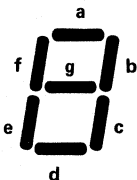
An internal latch option instead of the lamp test feature on the 8T7X series eliminates a quad latch (such as the 7475) from systems that require data storage. When the strobe input is LOW the input data is not stored and goes directly into the decoder ROM. The latch stores the information when the strobe line is high.

Low current PNP inputs (125µA max input current) make the 8T50/70 series CMOS compatible in addition to its inherent compatibility with standard 7400/8200 TTL.

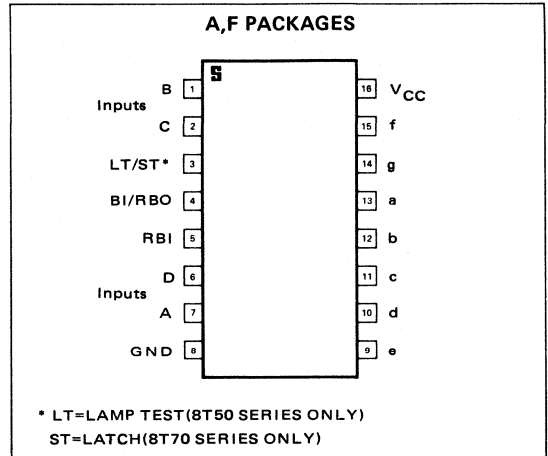
### FEATURES

- CONSTANT CURRENT OUTPUTS
- ELIMINATES 7 EXTERNAL RESISTORS
- DRIVES COMMON CATHODE OR COMMON ANODE LED DISPLAYS
- INTERNAL LATCH OR LAMP TEST
- PIN COMPATIBLE WITH STANDARD 7447 DECODER/DRIVER
- LOW INPUT CURRENT (125µA MAX)

### SEGMENT IDENTIFICATION



### PIN CONFIGURATIONS (Top View)



### DECODER DRIVER DEVICE TYPES CONSTANT CURRENT SEVEN SEGMENT LED

CONSTANT CURRENT SINK VERSIONS	
NON-LATCH	LATCH
N8T54B (20mA)	N8T74B (20mA)

CONSTANT CURRENT SOURCE VERSIONS	
NON-LATCH	LATCH
N8T51B (5mA)	N8T71B (5mA)
N8T59F (50mA)	N8T75B (20mA) (FSC 9368 Replacement)
	N8T79F (50mA)



**SIGNETICS CONSTANT CURRENT SEVEN SEGMENT LED DECODER/DRIVERS ■ 8T50/70**

**DC ELECTRICAL CHARACTERISTICS**  $V_{CC} = 5.0V \pm 5\%$ ,  $T_A = 0^\circ$  to  $+75^\circ C$

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
$I_{OL}$	LOW output current	16	20	24	mA	$V_{CC} = 5.0V$ , $T_A = 25^\circ C$ , $V_{OL} = 1.25V$
	8T54/74 "ON"					
	8T51/71 "OFF"					
	8T75 "OFF"					
	8T59/79 "OFF"					
BI/RBO	8					$V_{OL} = 0.45V$
$I_{OH}$	HIGH output current			250	$\mu A$	$V_{OH} = 5.5V$
	8T54/74 "OFF"					$V_{CC} = 5.0V$ , $T_A = 25^\circ C$ , $V_{OH} = 1.7V$
	8T51/71 "ON"	-4.0	-5	-6.0	mA	$V_{CC} = 5.0V$ , $T_A = 25^\circ C$ , $V_{OH} = 1.7V$
	8T75 "ON"	-16.0	-20	-24.0	mA	$V_{CC} = 5.0V$ , $T_A = 25^\circ C$ , $V_{OH} = 1.7V$
	8T59/79 "ON"	-40	-50	-60	mA	$V_{CC} = 5.0V$ , $T_A = 25^\circ C$ , $V_{OH} = 2.3V$
BI/RBO	-200			$\mu A$	$V_{OH} = 2.4V$	
$V_{IL}$	LOW input voltage			0.8	V	
$V_{IH}$	HIGH input voltage	2.0			V	
$V_I$	Input clamp voltage			-1.5	V	$I_{in} = -12mA$ , $V_{CC} = 5.25V$
$V_{in(max)}$	Maximum input voltage	5.5			V	$I_{in} = 1mA$ , $V_{CC} = 5.25V$
$I_{IL}$	LOW input current			-125	$\mu A$	$V_{IL} = 0.45V$
	All inputs except BI/RBO			-1.6	mA	$V_{IL} = 0.45V$
$I_{IH}$	HIGH input current			40	$\mu A$	$V_{IH} = 2.4V$
	All inputs except BI/RBO					
$I_{CC}$	Supply Current		40	60	mA	$V_{CC} = 5.25V$ over temperature

**AC CHARACTERISTICS 8T70 SERIES LATCH/DECODER/DRIVER**  $V_{CC} = 5.0V$ ,  $T_A = 25^\circ C$

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
$t_{setup}$	Minimum time before STROBE goes HIGH that input data must be stable		25	50	ns
$t_{hold}$	Minimum time after STROBE goes HIGH that input data must be stable	0	-24		ns
$t_{pw}$	Minimum STROBE pulse width to guarantee that input data will be stored		70	150	ns
$t_{pd}$	Propagation delay time from data input to segment output		150	400	ns

TRUTH TABLE

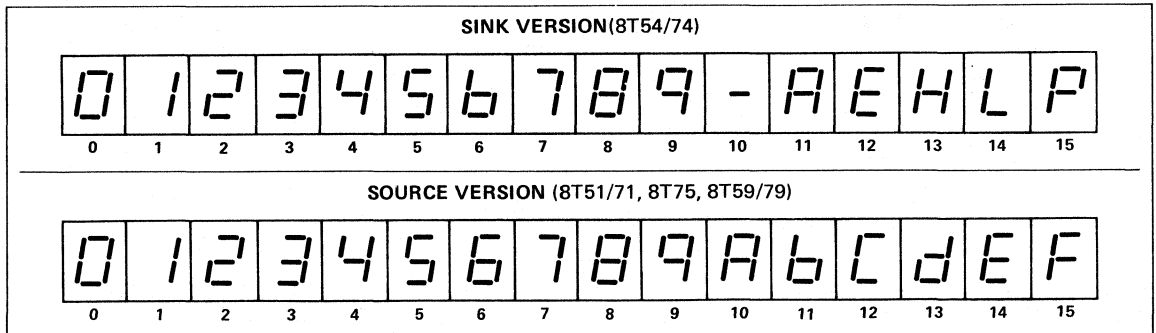
DECIMAL OR FUNCTION	INPUTS					BI/RBO†	SINK VERSION OUTPUTS							SOURCE VERSION OUTPUTS							NOTE	
	LT/ST	RBI	D	C	B		A	a	b	c	d	e	f	g	a	b	c	d	e	f		g
0	H	H	L	L	L	L	H	ON	ON	ON	ON	ON	ON	OFF	ON	ON	ON	ON	ON	ON	OFF	1
1	H	X	L	L	L	H	H	OFF	ON	ON	OFF	OFF	OFF	OFF	OFF	ON	ON	OFF	OFF	OFF	OFF	1
2	H	X	L	L	H	L	H	ON	ON	OFF	ON	ON	OFF	ON	ON	OFF	ON	ON	OFF	ON	ON	
3	H	X	L	L	H	H	H	ON	ON	ON	ON	OFF	OFF	ON	ON	ON	ON	OFF	OFF	ON	ON	
4	H	X	L	H	L	L	H	OFF	ON	ON	OFF	OFF	ON	ON	OFF	ON	ON	OFF	OFF	ON	ON	
5	H	X	L	H	L	H	H	ON	OFF	ON	ON	OFF	ON	ON	ON	OFF	ON	ON	OFF	ON	ON	
6	H	X	L	H	H	L	H	OFF	OFF	ON	ON	ON	ON	ON	ON	OFF	ON	ON	ON	ON	ON	
7	H	X	L	H	H	H	H	ON	ON	ON	OFF	OFF	OFF	OFF	ON	ON	ON	OFF	OFF	OFF	OFF	
8	H	X	H	L	L	L	H	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	
9	H	X	H	L	L	H	H	ON	ON	ON	OFF	OFF	ON	ON	ON	ON	ON	OFF	OFF	ON	ON	
10	H	X	H	L	H	L	H	OFF	OFF	OFF	OFF	OFF	OFF	ON	ON	ON	ON	OFF	ON	ON	ON	
11	H	X	H	L	H	H	H	ON	ON	ON	OFF	ON	ON	ON	ON	ON	ON	OFF	OFF	ON	ON	
12	H	X	H	H	L	L	H	ON	OFF	OFF	ON	ON	ON	ON	ON	ON	ON	OFF	ON	ON	OFF	
13	H	X	H	H	L	H	H	OFF	ON	ON	OFF	ON	ON	ON	ON	ON	ON	OFF	ON	ON	OFF	
14	H	X	H	H	H	L	H	OFF	OFF	OFF	ON	ON	ON	OFF	ON	ON	ON	OFF	ON	ON	ON	
15	H	X	H	H	H	H	H	ON	ON	OFF	OFF	ON	ON	ON	ON	ON	ON	OFF	OFF	ON	ON	
BI	H	X	X	X	X	X	L	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	2
RBI	H	L	L	L	L	L	L	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF	3
LT/ST*	L	X	X	X	X	X	X	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	ON	4,5

H = High Level, L = Low Level, X = Irrelevant, † BI/RBO is wired AND logic, serving as a blanking input (BI) and/or ripple blanking output (RBO).  
 \*8T50 Series has lampstest (LT)  
 8T70 Series has strobe (ST)

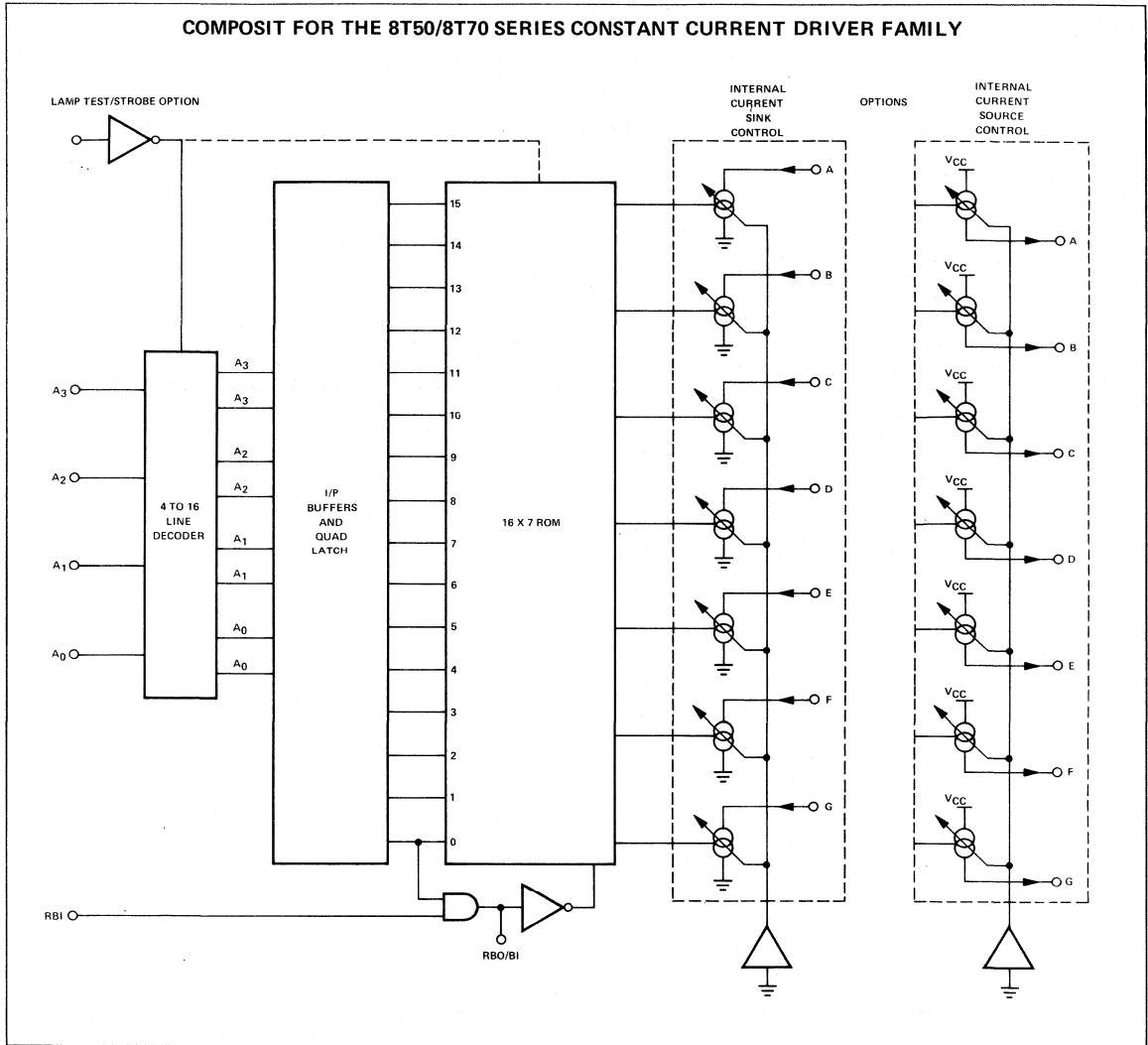
NOTES

1. The blanking input (BI) must be open or held at a high logic level when output functions 0 through 15 are desired. The ripple-blanking input (RBI) must be open or high if blanking of a decimal zero is not desired.
2. When a low logic level is applied directly to the blanking input (BI), all segment outputs are off regardless of the level of any other input. BI should not be forced high, when inputs A, B, C, D and RBI are low.
3. When the ripple blanking input (RBI) is at a low level and the inputs A, B, C, and D are at a low level with the lamp test input (LT) high (for the 8T50 series) or when a binary zero is stored in the latches (8T70 series) all segment outputs go off and the ripple blanking output (RBI) goes to a low level (response condition).
4. When a low is applied to the lamp test input (LT) of the 8T50 series devices all segment outputs are on. The 8T70 series devices do not have a lamp test input but a strobe input instead.
5. The 8T50 series devices have a lamp test input (LT) whereas the 8T70 series devices have a strobe input (ST). Input data is directly transferred to the outputs when the strobe is low and is stored when the strobe is high.

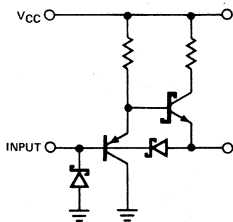
RESULTANT DISPLAY PATTERNS



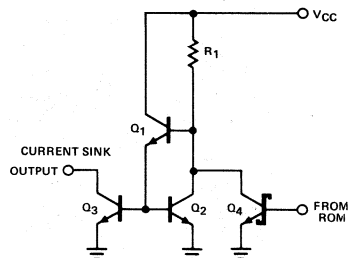
LOGIC DIAGRAM



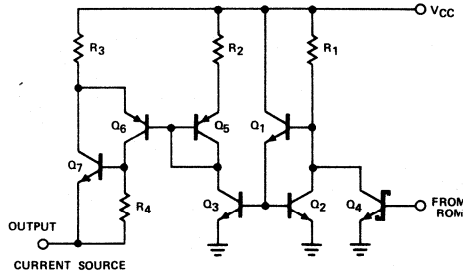
**8T50/70 SERIES LOW CURRENT PNP INPUT STRUCTURES**



**8T50/70 OUTPUTS FOR CURRENT SINK VERSION**

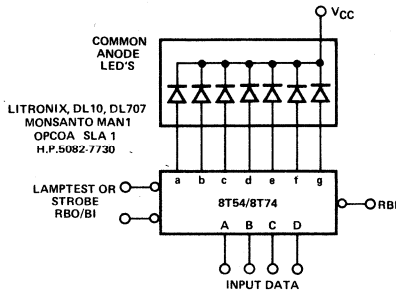


8T50/70 OUTPUTS FOR CURRENT SOURCE VERSION

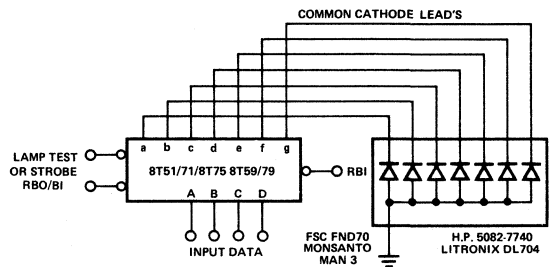


TYPICAL APPLICATIONS

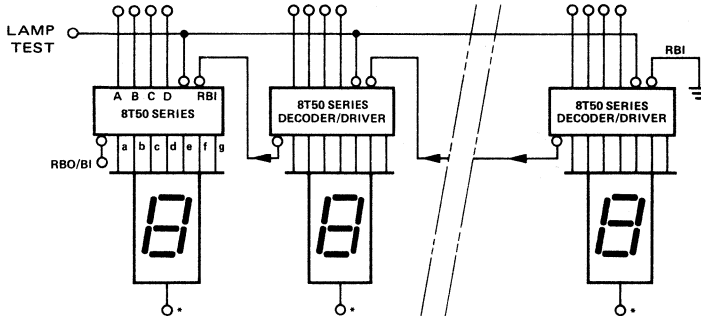
DRIVING COMMON ANODE LED'S  
(CONSTANT CURRENT SINK VERSION)



DRIVING COMMON CATHODE LED'S  
(CONSTANT CURRENT SOURCE VERSION)

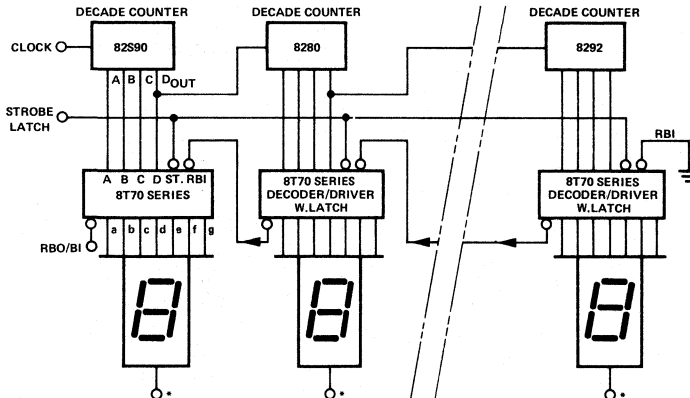


8T50 SERIES WITH LAMP TEST (LT)



\*TIE TO V<sub>CC</sub> FOR COMMON ANODE LED'S;  
OTHERWISE TIE TO GROUND FOR COMMON  
CATHODE LED'S.

8T70 SERIES WITH INTERNAL LATCH USED IN FREQUENCY COUNTER



\*TIE TO V<sub>CC</sub> FOR COMMON ANODE LED'S;  
OTHERWISE TIE TO GROUND FOR COMMON  
CATHODE LED'S.

DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

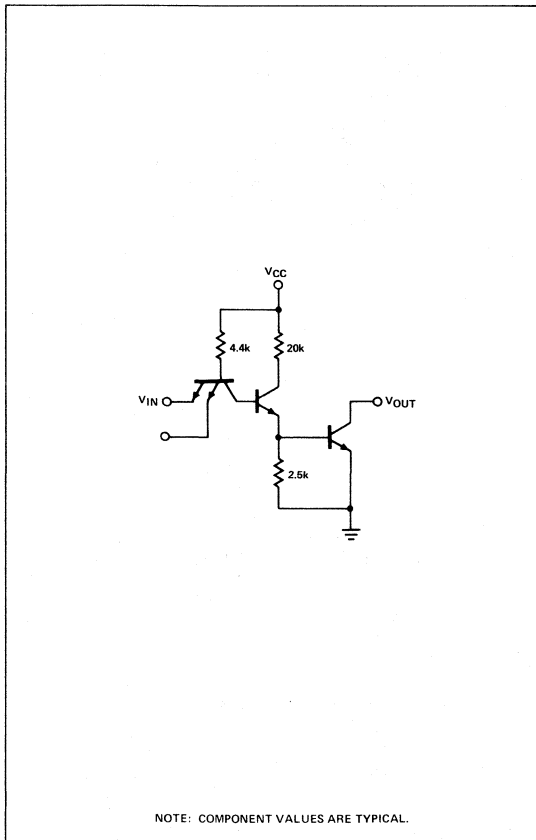
The 8T80 quad 2-input NAND interface gate and the 8T90 Hex inverter interface buffer are level translators that adapt standard 5V DTL/TTL logic to voltage levels of up to 30V.

The 8T80 performs the NAND function for positive logic (high level = logic "1") and the 8T90 performs the inverting function.

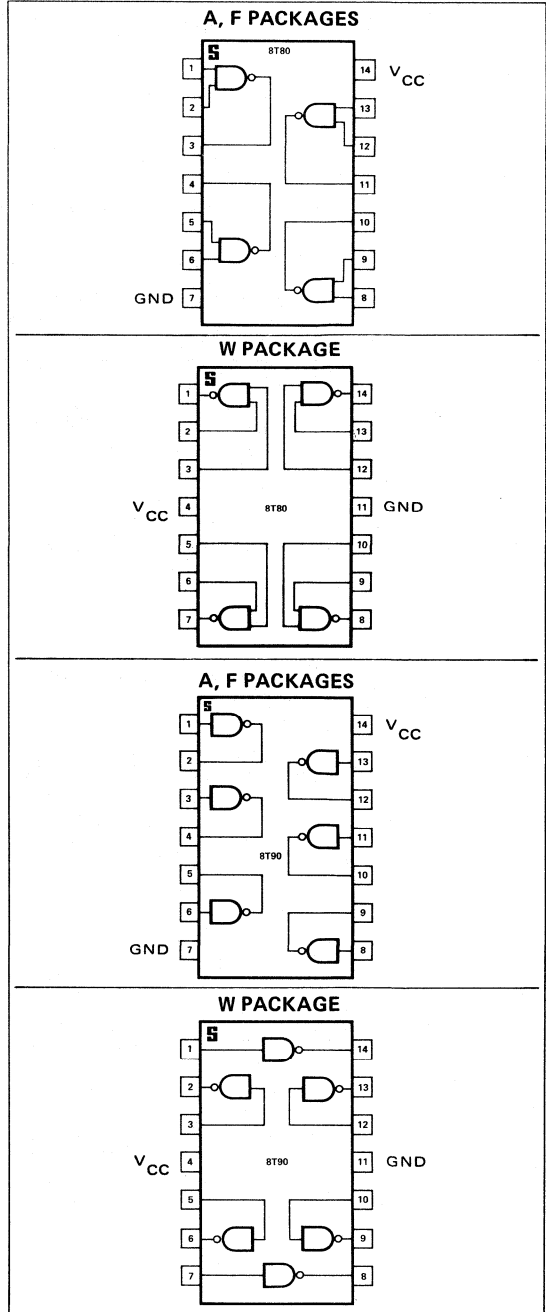
The output structure of the 8T80/90 is a high voltage transistor with uncommitted collector which allows logic swings up to 30 volts. The "bare" collector is useful for collector logic or wired-and connections.

Applications include TTL to MOS interface, lamp and relay driving as well as high level logic interfaces.

### CIRCUIT SCHEMATIC



### PIN CONFIGURATIONS (Top View)



DC CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS				
	MIN.	TYP.	MAX.	UNITS	V <sub>CC</sub>	DRIVEN INPUT	OTHER INPUTS	OUTPUTS	NOTES
"1" OUTPUT LEAKAGE CURRENT			100	μA		0.6V			7
"0" OUTPUT VOLTAGE			1.0	V		2.0V	2.0V	20mA	8
"0" OUTPUT VOLTAGE			0.35	V		2.0V	2.0V	7.2mA	8,9
"0" INPUT CURRENT	-0.1		-1.6	mA		0.35V	5.25V		
"1" INPUT CURRENT			25	μA		4.5V	0V		
POWER CONSUMPTION OUTPUT "0"			20.0	mW	5.25V				
(Per Gate) OUTPUT "1"			7.9	mW	5.25V	0V			
OUTPUT VOLTAGE RATING	40			V		0V			11

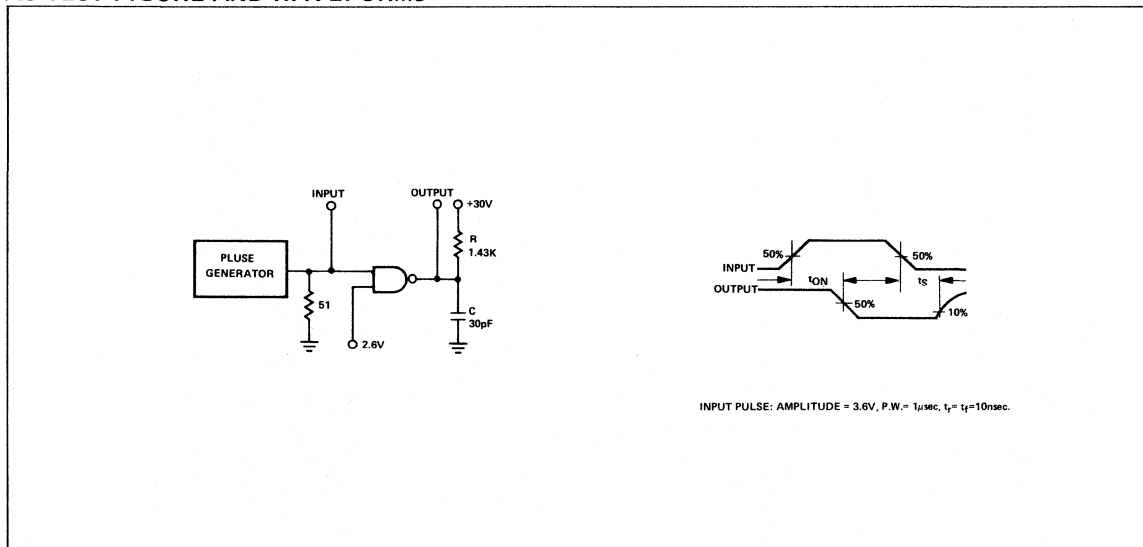
AC CHARACTERISTICS T<sub>A</sub> = 25°C, V<sub>CC</sub> = 5.0V

CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Turn-on Delay		35	55	ns	R <sub>L</sub> = 1.43K	12
Storage Time		40	95	ns	C <sub>L</sub> = 30pF	

NOTES

- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each gate element independently.
- Output leakage current is supplied through a 2KΩ resistor to 30V.
- Output sink current is supplied through a resistor to 30V.
- This test applies to 8T90 only.
- "OTHER INPUTS" applies to 8T80 only.
- For this test, connect a 2KΩ resistor from output under test to 41V and a 10pF capacitor from output to ground. V<sub>CC</sub> = 5.0V.
- See AC Test Circuit and Waveforms.

AC TEST FIGURE AND WAVEFORMS



### PRELIMINARY SPECIFICATION

### DIGITAL 8T SERIES INTERFACE TTL/MSI

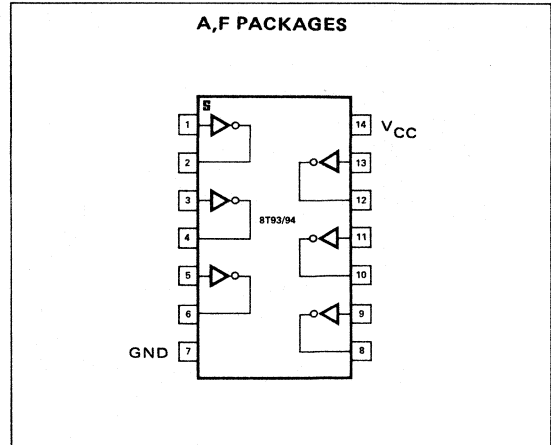
### DESCRIPTION

The 8T93/94 Hex Inverter interface elements have been designed with Schottky TTL technology. This makes it possible to combine ultra-high speed with a low current PNP input structure. Because of their low input current requirements the 8T93/94 are ideal in applications such as bus receivers, low power TTL interfaces as well as MOS and C-MOS to TTL buffers. The 8T93 has active pullups while the 8T94 features open collectors.

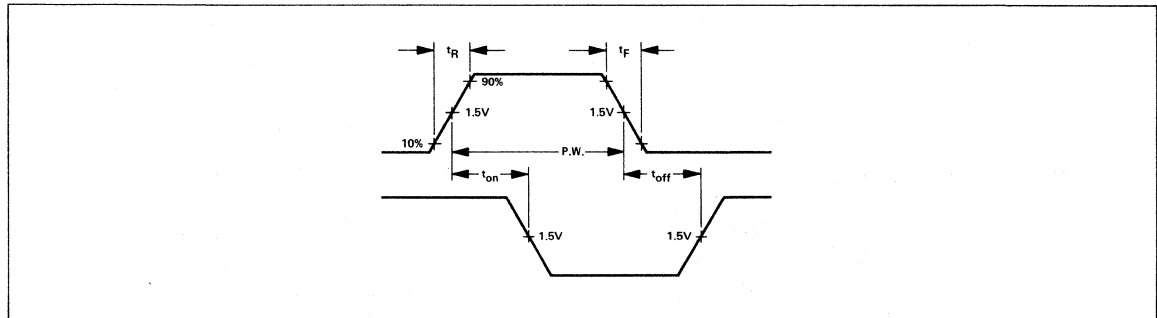
### FEATURES

- LOW CURRENT PNP INPUTS
- SCHOTTKY TTL DESIGN
- TTL/DTL & MOS/C-MOS COMPATIBLE
- 8T94 HAS OPEN COLLECTOR OUTPUTS
- PIN COMPATIBLE WITH 74S04 AND 74S05

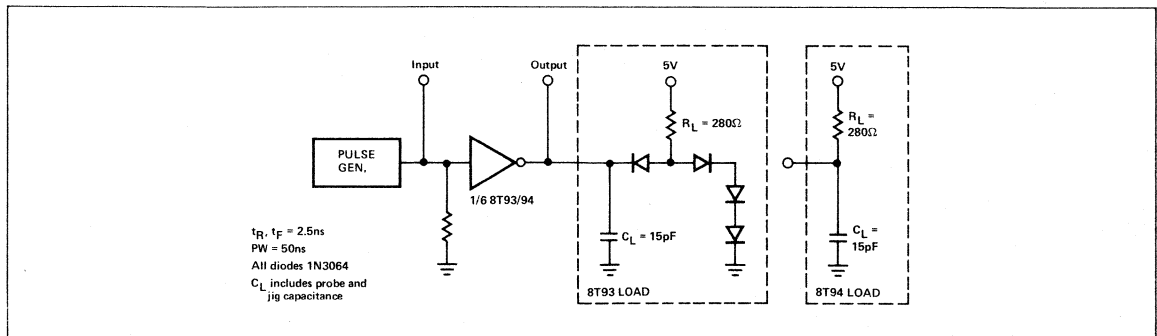
### PIN CONFIGURATIONS (Top View)



### AC WAVEFORMS



### AC TEST FIGURE



**DC ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS		NOTES
	MIN	TYP	MAX	UNITS	INPUT	OUTPUT	
"1" Output Voltage (8T93)	2.7	3.3		V	0.8V	-1mA	6
"0" Output Voltage			0.5	V	2.0V	20mA	7
"1" Output Leakage (8T94)			250	$\mu$ A	0.8V	5.5V	9
"0" Input Current			-400	$\mu$ A	0.5V		
"1" Input Current			10	$\mu$ A	4.5V		
Output Short Circuit Current (8T93)	-40		-100	mA	0V	0V	10,11
Input Voltage Rating	5.5			V	1mA		
Input Clamp Voltage	-1.2			V	-18mA		
Supply Current 8T93		15	24	mA	0V		10
(All Outputs High) 8T94		9	20	mA	0V		10
(All Outputs Low) 8T93/94		30	54	mA			10

**AC ELECTRICAL CHARACTERISTICS**  $T_A = 25^{\circ}\text{C}$ ,  $V_{CC} = 5\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Propagation Delay						
(8T93) $t_{on}$ , $t_{off}$		5		ns	$R_L = 280$	8
(8T94) $t_{on}$ , $t_{off}$		6		ns	$C_L = 15\text{ pF}$	

**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" level = "1"; "DOWN" = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figures and Test Table.
- Connect an external  $1\text{K} \pm 1\%$  resistor to 5.5V for this test.
- $V_{CC} = 5.25\text{V}$ .
- Not more than one output should be shorted at a time.



### PRELIMINARY SPECIFICATION

### DIGITAL 8T SERIES INTERFACE TTL/MSI

### DESCRIPTION

Each of the Tri-State Bus Interface Elements described herein has low current PNP inputs and is designed with Schottky TTL technology for ultra high speed. The devices are used to convert TTL/DTL or MOS/CMOS to tri-state TTL Bus levels. For maximum systems flexibility the 8T95 and 8T97 do so without logic inversion, whereas, the 8T96 and 8T98 provide the logical complement of the input. The 8T95 and 8T96 feature a common control line for all six devices, whereas, the 8T97 and 8T98 have control lines for four devices from one input and two from another input.

### FEATURES

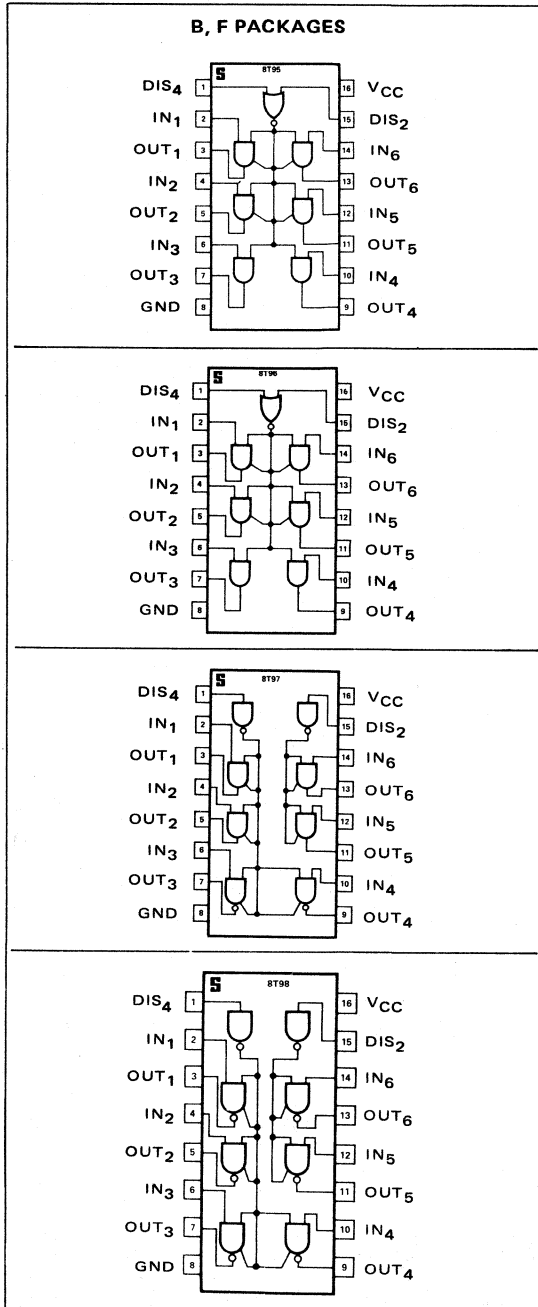
- LOW CURRENT PNP INPUTS (400 $\mu$ A)
- HIGH SPEED SHOTTKY TTL DESIGN (TYP. 8ns)
- TTL/DTL, MOS/CMOS COMPATIBLE
- LOW POWER DISSIPATION
  - 8T95/97 TYP. 325mW
  - 8T96/98 TYP. 295mW
- HIGH SPEED REPLACEMENTS FOR
  - DM 8095 = 8T95
  - DM 8096 = 8T96
  - DM 8097 = 8T97
  - DM 8098 = 8T98

### TRUTH TABLES

8T95			
DISABLE DIS <sub>1</sub>	INPUT DIS <sub>2</sub>	INPUT	OUTPUT
0	0	0	0
0	0	1	1
0	1	x	H-z
1	0	x	H-z
1	1	x	H-z

8T96			
DISABLE DIS <sub>1</sub>	INPUT DIS <sub>2</sub>	INPUT	OUTPUT
0	0	0	1
0	0	1	0
0	1	x	H-z
1	0	x	H-z
1	1	x	H-z

### PIN CONFIGURATIONS (Top View)



TRUTH TABLES (Cont'd)

8T97			
DISABLE DIS <sub>4</sub>	INPUT DIS <sub>2</sub>	INPUT	OUTPUT
0	0	0	0
0	0	1	1
x	1	x	H-z*
1	x	x	H-z**

8T98			
DISABLE DIS <sub>4</sub>	INPUT DIS <sub>2</sub>	INPUT	OUTPUT
0	0	0	1
0	0	1	0
x	1	x	H-z*
1	x	x	H-z**

\*Output 5-6 only \*\*Output 1-4 only x = Irrelevant

DC ELECTRICAL CHARACTERISTICS Over Recommended Voltage and Temperature Range

CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Logical "1" Input Voltage	2.0			V	$V_{CC} = \text{Min } T_A = 25^\circ\text{C}$	
Logical "0" Input Voltage			0.8	V	$V_{CC} = \text{Min } T_A = 25^\circ\text{C}$	
Logical "1" Output Voltage	2.4			V	$V_{CC} = \text{Min}$ $I_0 = -5.2 \text{ mA}$	6
Logical "0" Output Voltage			0.5	V	$I_{\text{out}} = 48 \text{ mA}$	7
Third State Input Current			-40	$\mu\text{A}$	$V_{CC} = \text{Max}$ $V_{\text{in}} = 0.5\text{V}$ DIS = 2.0V	
Third State Output Current			40 -40	$\mu\text{A}$ $\mu\text{A}$	$V_{CC} = \text{Max}$ $V_o = 2.4\text{V}$ $V_o = 0.5\text{V}$	
Logical "1" Input Current			40	$\mu\text{A}$	$V_{CC} = \text{Max}$ $V_{\text{in}} = 2.4\text{V}$	
Logical "0" Input Current			-400	$\mu\text{A}$	$V_{CC} = \text{Max}$ $V_{\text{IN}} = 0.5\text{V}$ DIS = 0.5V	
Output Short Circuit Current	-40	-80	-115	mA	$V_{CC} = \text{Max}$ $V_o = 0\text{V}$	9, 10
Supply Current (each device)			65 59	98mA 89mA	$V_{CC} = \text{Max}$	
Input Voltage Rating	5.5			V	$I_{\text{in}} = 1 \text{ mA}$	
Input Clamp Voltage			-1.5	V	$V_{CC} = \text{Min}$ $I_{\text{in}} = -12 \text{ mA}$	
Output $V_{CC}$ Clamp Voltage			1.5	V	$V_{CC} = 0\text{V}$ $I_o = 12 \text{ mA}$	
Output Ground Clamp Voltage			-1.5	V	$V_{CC} = 0\text{V}$ $I_o = -12 \text{ mA}$	

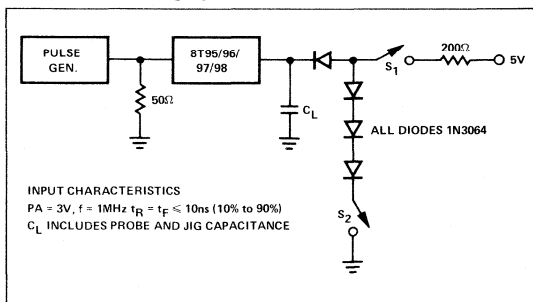
AC ELECTRICAL CHARACTERISTICS  $T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Propagation Delays (All Devices)					See AC Test Figures	8
Data Inputs $t_{on}$ to Data Outputs $t_{off}$		5				
Disable to Outputs						
Logic "1" to High Z $t_{PIH}$		4		ns		
Logic "0" to High Z $t_{POH}$		6		ns		
High Z to Logic "1" $t_{PHI}$		10		ns		
High Z to Logic "0" $t_{PHO}$		12		ns		

NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" level = "1"; "DOWN" = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figures and Test Table.
- $V_{CC} = 5.25\text{V}$ .
- Not more than one output should be shorted at a time.

AC TEST CIRCUIT

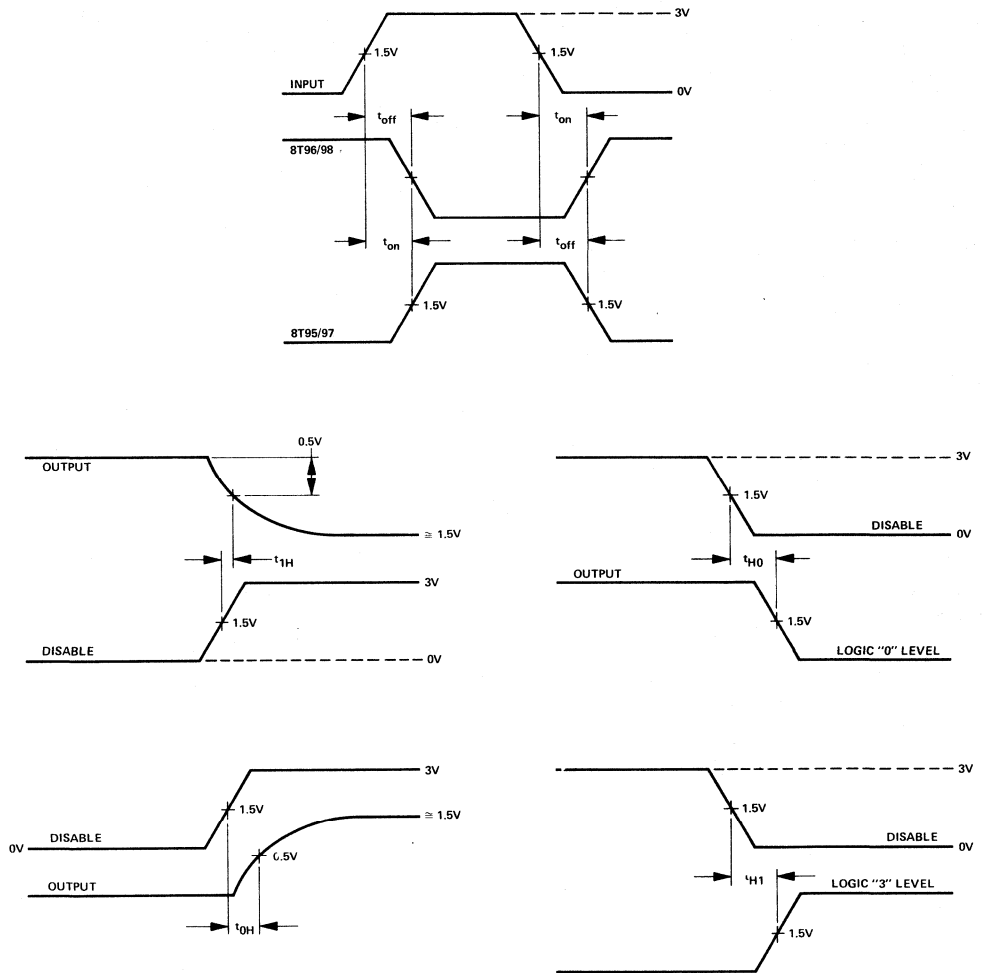


TRUTH TABLE

	$S_1$	$S_2$	$C_L$
$t_{on}$	Closed	Closed	50pF
$t_{off}$	Closed	Closed	50pF
$t_{0H}$	Closed	Closed	5pF
$t_{1H}$	Closed	Closed	5pF
$t_{H0}$	Closed	Open	50pF
$t_{H1}$	Open	Closed	50pF

AC WAVEFORMS

PROPAGATION DELAYS



TO BE ANNOUNCED

DIGITAL 8T SERIES INTERFACE TTL/MSI

Two TTL Compatible Transmission Line Interface Circuits Designers have been waiting for:

### 8T100 QUAD DIFFERENTIAL LINE DRIVER

#### FEATURES

- SINGLE 5V POWER SUPPLY
- ULTRA HIGH SPEED
- FOUR DRIVERS PER IC
- BALANCED DIFFERENTIAL OUTPUTS
- TRI-STATE/PARTY LINE OPERATION

### 8T110 QUAD DIFFERENTIAL LINE RECEIVERS

#### FEATURES

- SINGLE 5V POWER SUPPLY
- ULTRA HIGH SPEED
- FOUR RECEIVERS PER IC
- HIGH COMMON MODE RANGE
- HIGH NOISE IMMUNITY

DIGITAL 8T SERIES INTERFACE TTL/MSI

## DESCRIPTION

The 8T363 Dual Zero Crossing Detector is an interface circuit incorporating a differential amplifier input and logic gate output. The input amplifier is referenced to zero volts and employs temperature compensation to ensure stable thresholds. The output structure of the 8T363 is compatible with DTL and TTL circuits.

## APPLICATIONS

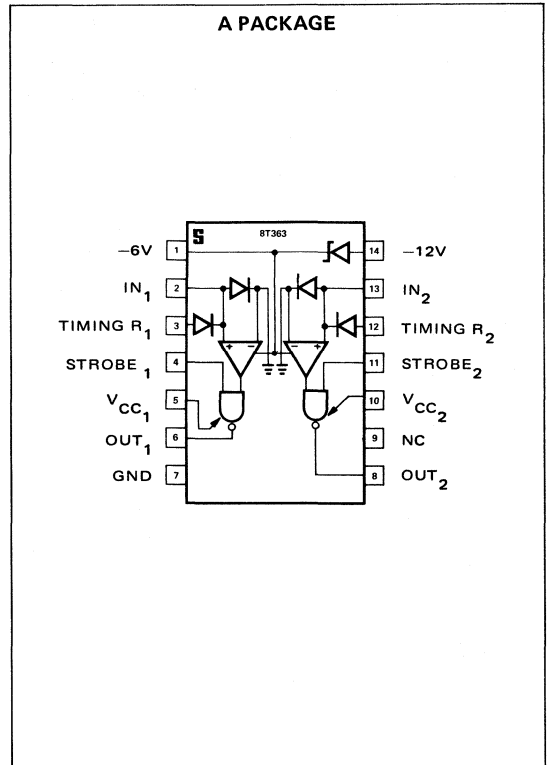
- ZERO-CROSSING DETECTOR
- HIGH STABILITY ONE-SHOT
- BI-DIRECTIONAL ONE-SHOT
- FREQUENCY DOUBLER
- STABLE-LOW FREQUENCY OSCILLATOR
- LINEAR AMPLIFIER
- FREQUENCY TO VOLTAGE CONVERTER

## ABSOLUTE MAXIMUM RATINGS

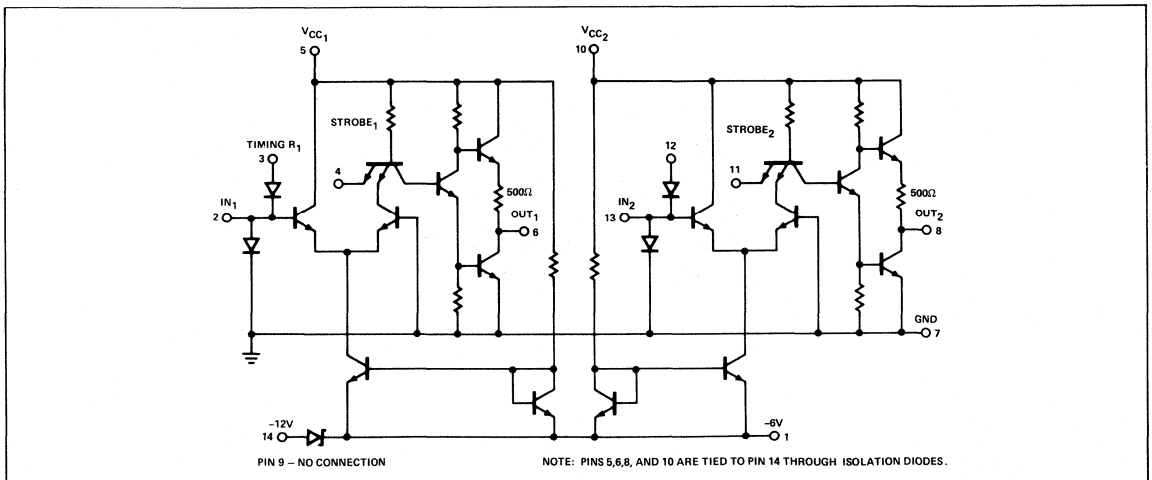
Input Voltage	+7.0V
Output Voltage	+6.0V
V <sub>CC</sub>	+6.0V
Input Current	±10mA
Output Current	+30, -10mA
Storage Temperature	-65°C to +175°C
Operating Temperature	0°C to +75°C
V-	-7V or -13.5V

Maximum ratings are limiting values above which serviceability may be impaired.

## PIN CONFIGURATION (Top View)



## CIRCUIT SCHEMATIC



**DC ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature $V_{CC} = 5V \pm 5\%$   $V^- = -6V \pm 5\%$  or  $V^- = 12V \pm 5\%$ 

CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
"1" Output Voltage	2.6	3.2		V	V signal = -30mV, $I_{out} = -400\mu A$
"0" Output Voltage			0.6 0.4	V V	V signal = +30mV, $I_{out} = 12.5mA$ $I_{out} = 7.5mA$
"1" Input Current Strobe			40	$\mu A$	Note 9, V strobe = 2.4V, $V_7 = V_3 = V_{12}$
Input High Signal			100	$\mu A$	V signal = 100mV
"0" Input Current Strobe			-1.4	mA	V signal = $V_{CC}$ through 10K $\Omega$ resistor, V strobe = 0.6V
Input Voltage (Timing R $V_F$ Diode)			1	V	$V_7 = V_2 = V_{13}$ , $I_3 = 1mA$ , $I_{12} = 1mA$
Uncertainty Region-Signal			$\pm 30$	mV	
I <sub>cc</sub> /Detector			6.5	mA	$V_7 = V_3 = V_{12}$ , Note 9, $T_A = 25^\circ C$
I <sub>EE</sub>			-13.0	mA	

NOTE: Pin 14 must be tied to the most negative voltage used, when  $V^- = -6V$ , Pin 14 must be tied to Pin 1.**AC ELECTRICAL CHARACTERISTICS**  $T_A = 25^\circ C$ ,  $V_{CC} = 5.0V$ ,  $V^- = -6V$ 

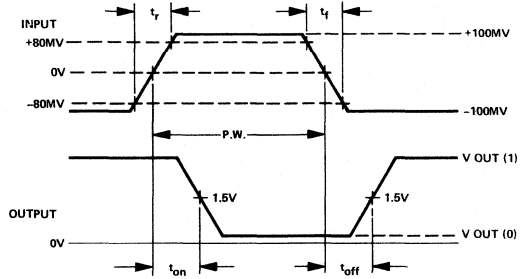
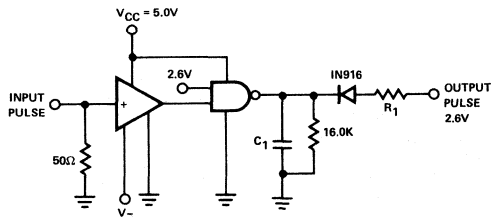
CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
Turn on Delay				ns	See Test Figure 1, $T_A = 25^\circ C$
Detector			85		See Test Figure 2, V signal = $V_{CC}$ through
Strobe to Output			50	ns	10K $\Omega$ resistor, $T_A = 25^\circ C$
Turn off Delay				ns	See Test Figure 1, $T_A = 25^\circ C$
Detector			65		See Test Figure 2, V signal = $V_{CC}$ through
Strobe to Output			50	ns	10K $\Omega$ resistor, $T_A = 25^\circ C$

## NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive NAND Logic Definition: "UP" level = "1", "DOWN" level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each gate element independently.

AC TEST FIGURES AND WAVEFORMS

$t_{on}$ ,  $t_{off}$  DETECTOR INPUTS



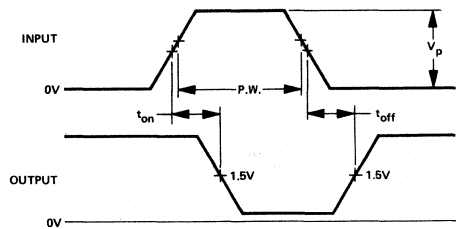
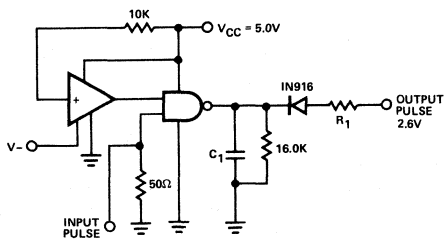
$t_{on}$	$t_{off}$
$C_1 = 27\text{pF}$	$18\text{pF}$
$R_1 = 210\Omega$	$1.91\text{k}\Omega$

Input Pulse;  $V_{in}$

Pulse Width = 350ns at 50% Points  
 $t_r = t_f = 10\text{ns}$   
 Amplitude =  $\pm 100\text{mV}$

FIGURE 1.

$t_{on}$ ,  $t_{off}$  STROBE TO OUTPUT



$t_{on}$	$t_{off}$
$C_1 = 27\text{pF}$	$18\text{pF}$
$R_1 = 210\Omega$	$1.91\text{k}\Omega$

Input Pulse;  $V_{in}$

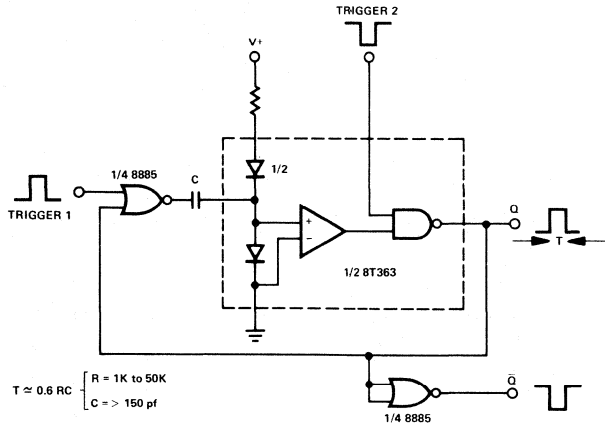
Pulse Width = 200ns at 50% Points  
 $t_r = t_f$  (10%-90%) = 10ns  
 Amplitude  $V_p = 4.0\text{V}$

FIGURE 2.

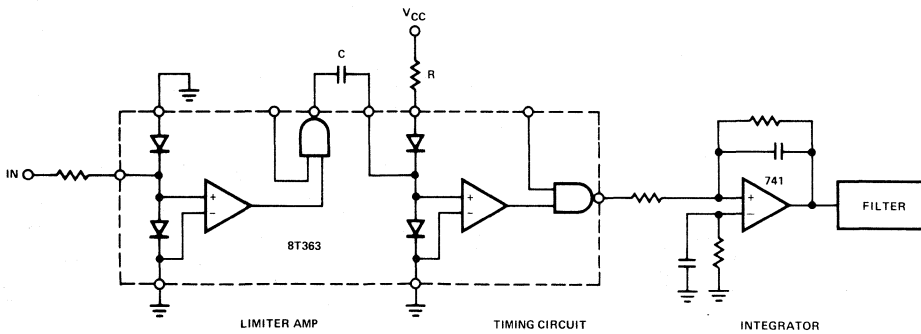


TYPICAL APPLICATIONS

MONOSTABLE MULTIVIBRATOR



FREQUENCY TO VOLTAGE CONVERTER



Sine wave inputs up to approximately 500 KHz are limited, amplified and used to trigger the timing circuit. The timing circuit output is a constant pulse width ( $pw \approx 0.6RC$ ). The constant width pulses are integrated and then filtered to attenuate the remaining high frequency carrier components.

## PRELIMINARY SPECIFICATION

DIGITAL 8T SERIES INTERFACE TTL/MSI

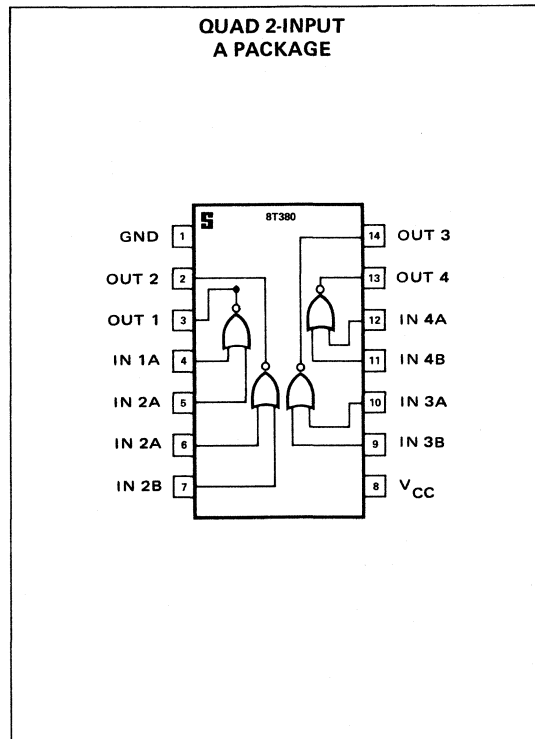
### DESCRIPTION

The 8T380 is a quad 2-input bus receiver with hysteresis for use in I/O, data, and memory busses. Built in hysteresis provides maximum noise immunity and a power-up or power-down sequence on the receiver will not affect the bus. Low input current allows several drivers and receivers to communicate over a common bus in "Party Line" fashion. The receiver has been designed to be pin-compatible with the Signetics Utilogic II SP 380 gate and provides increased noise immunity as well as lower input current. The 8T380 is ideal as a Schmitt Trigger in analog interfaces that cannot tolerate the non-linear input impedance characteristics of standard TTL. Further, the low input requirements allow the 8T380 to be used as a CMOS to TTL interface. All inputs have clamping diodes to simplify systems design.

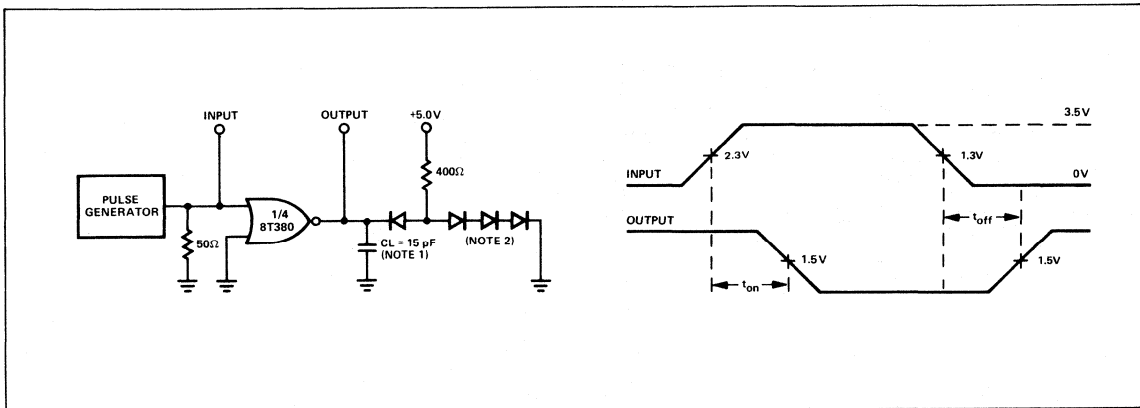
### FEATURES

- HIGH SPEED (TYP. 18ns)
- LOW INPUT CURRENT (TYP. 15 $\mu$ A)
- BUILT IN HYSTERESIS (TYP. 1V)
- HIGH NOISE IMMUNITY (TYP. 1.6V)
- TTL/DTL COMPATIBLE
- CMOS COMPATIBLE LOW CURRENT INPUTS
- INPUT CLAMP DIODES
- SP380/DM8836 PLUG-IN REPLACEMENT

### PIN CONFIGURATION (Top View)



### AC TEST FIGURE AND WAVEFORMS



#### NOTES

1. Including probe and jig capacitance
  2. All diodes are 1N3064
  3. Pulse generator characteristics
- 3-206

P.A. = 3.5V  
 $Z_{OUT} = 50\Omega$   
 $PRR = 1\text{MHz}$   
 $t_r = t_f \leq 10\text{ns}$  (10% to 90%)  
 Duty Cycle = 50%

**DC ELECTRICAL CHARACTERISTICS** Over Recommended Temperature Range and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUT A	INPUT B	OUTPUT	
"1" Output Voltage	2.4			V	V <sub>TH</sub> (0)	0V	-400μA	6, 12
					0V	V <sub>TTH</sub> (0)		
"0" Output Voltage			0.4	V	V <sub>TH</sub> (1)	0V	16mA	7, 12
					0V	V <sub>TH</sub> (1)		
Maximum Input Current		15	50	μA				9
		1	50	μA				10
High Level Input Threshold V <sub>TH</sub> (1)	2	2.25	2.5	V			16mA	12
Low Level Input Threshold V <sub>TH</sub> (0)	1.1	1.3	1.5	V			-400μA	12
Input Clamp Voltage (All Inputs) T <sub>A</sub> = 25°C			-1.5	V	-12mA	-12mA		
Output Short Circuit Current, I <sub>OS</sub>	-18		-55	mA	0.5V	0.5V	0V	11
Power/Current Consumption		132/25	210/40	mW/mA	4V	4V		9

**AC ELECTRICAL CHARACTERISTICS** T<sub>A</sub> = 25°C, V<sub>CC</sub> = 5.0V

CHARACTERISTIC	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
Turn-on Delay, t <sub>on</sub>		16	35	ns	See AC Test Figure and Waveforms C <sub>L</sub> = 15 pF, R <sub>L</sub> = 400Ω.
Turn-off Delay, t <sub>off</sub>		20	35	ns	

**NOTES**

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic definition:  
"UP" Level = "1" "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Manufacturer reserves the right to make design and process changes and improvements.
- V<sub>CC</sub> = 5.25 volts.
- V<sub>CC</sub> = 0 volts.
- Not more than one output should be shorted at a time.
- Each input is tested separately.

**TYPICAL APPLICATIONS**

A generalized "Party Line" bus interface is shown in Figure 1. Each driver/receiver combination can communicate with any other pair or all. Open collector Nand Gates such as the Signetics 7439 have adequate drive capability for the bus terminations as well as 20 driver/receiver pairs. In addition the bussing scheme is non-inverting as shown and bus drivers are activated by a logic "1" whereas bus receivers are activated by a Logic "0".

Each terminator consisting of a 180 ohm resistor to V<sub>CC</sub> and a 390 ohm resistor to ground is a 120 ohm. Thevenin's equivalent circuit. The maximum length of cable that can be driven is a complex relationship involving the type of cable used as well as the distribution of drivers and receivers on the buss. Using flat ribbon cable, a maximum reasonable length is 50 ft. minus the combined length of all taps or stubs.

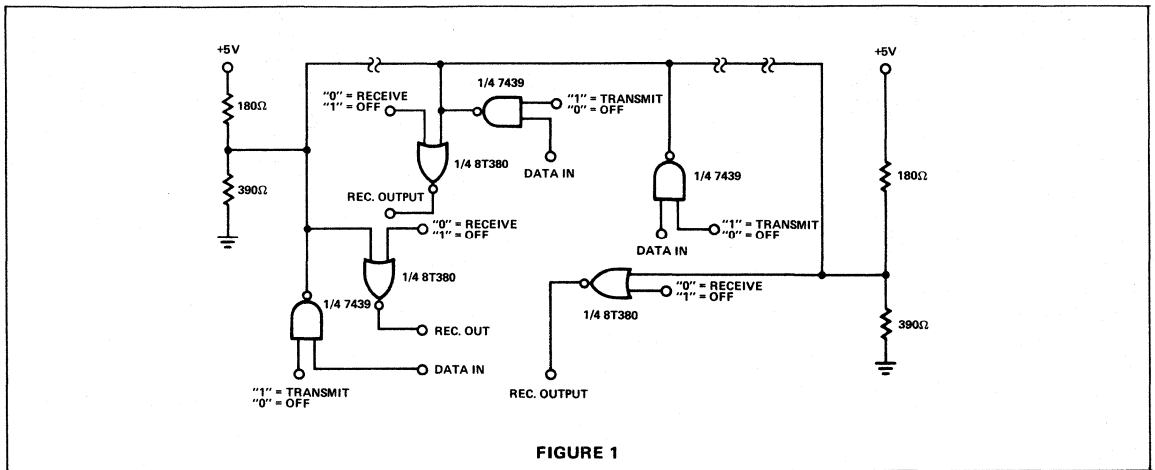


FIGURE 1

**SCHMITT TRIGGER**

The receiver transfer curve shown in Figure 2a makes the 8T380 ideal in a variety of Schmitt Trigger and wave-shaping applications such as Figure 2b.

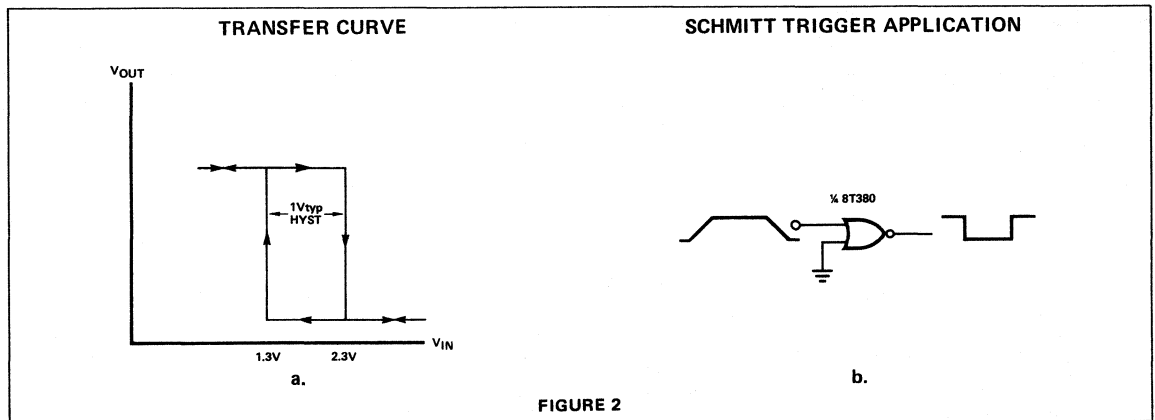


FIGURE 2

**MOS/C-MOS INTERFACE**

The low input current which is only 50μA max. in the logical "1" state and no current in the logical "0" state makes the 8T380 an ideal MOS/C-MOS interface element.

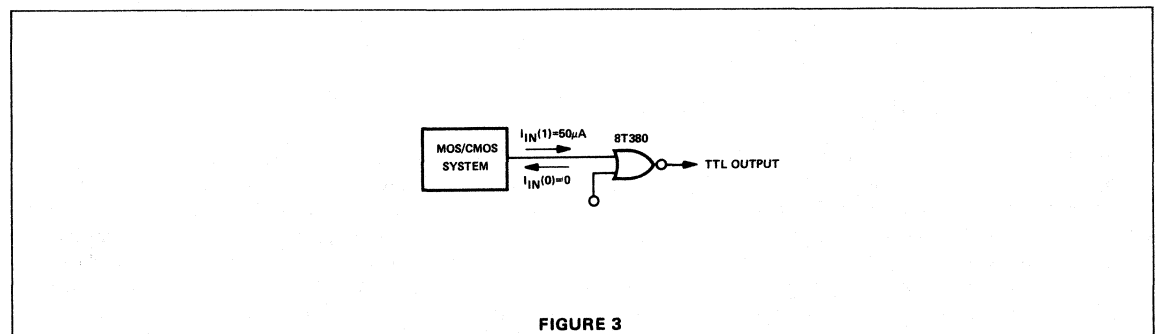


FIGURE 3

## INTRODUCTION AND ORDERING INFORMATION

## INTRODUCTION

The 82S Optimized Schottky MSI circuits are described in this section. These devices are directly compatible with the 82S Bipolar Memories described in the following section and other TTL circuits such as the 8000 MSI circuits and 8000 Bipolar Memories, the 54/74 series and 54S/74S described in the Signetics Integrated Circuits Handbook.\*

The electrical specifications given for the integrated circuits in this booklet are designed to serve as an exact guide for procurement documents. Detailed test conditions and test limits are given for each integrated circuit. Whenever possible, worst case limits for the electrical parameters have been provided.

Ordering information for the circuits described in this section can be found below. This information should be

reviewed in conjunction with detailed package descriptions given in the appendix where physical dimensions as well as thermal impedance data are given.

Reliability information that details production screens, acceptance tests and qualification tests is given in the Signetics Integrated Circuits Handbook.\* The users attention is also directed to the optional high reliability programs described therein. These are the Signetics SUPR DIP Program for plastic packages and the Signetics SURE 883 program.

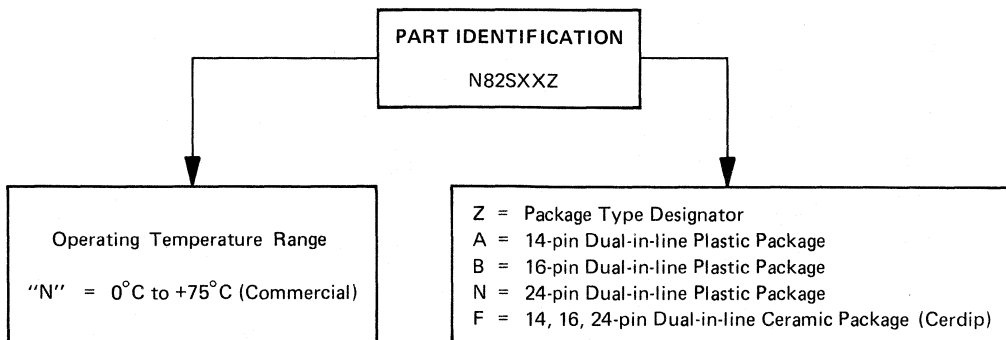
Detailed applications ideas are given in the Signetics Applications Handbook\* and Schottky Systems Design Application Notes\*. Additional applications information may be obtained from the nearest Signetics representative or local Signetics field applications engineer.

## ORDERING INFORMATION

Unless otherwise specified all devices are available in the commercial ("N") temperature ranges:

"N" = 0°C to +75°C

The package type designators below, in conjunction with detailed package information given in the appendix may be used for procurement purposes.



\* Available by filling out the Literature Request Card in the Appendix.

**FEATURES**

- 3 ns TYPICAL GATE PROPAGATION DELAY
- 20 mW PER GATE TYPICAL POWER DISSIPATION
- LOW CURRENT PNP INPUTS (400µA MAX.)
- SCHOTTKY DIODE CLAMPED INPUTS
- HIGH OUTPUT DRIVE CAPABILITY

**BENEFITS**

- COMPATIBLE WITH 8000 SERIES, 54/74, 54S/74S TTL AS WELL AS DTL AND C-MOS
- TERMINATED, CONTROLLED IMPEDANCE LINES NOT NORMALLY REQUIRED
- DRIVES HIGH CAPACITIVE LOADS
- LOW A.C. NOISE SUSCEPTIBILITY

**FUNCTION TABLE**

FUNCTION		TYPICAL SPEED	COMMENTS
82S30	8-Input Digital Multiplexer	7 ns	Replaces FSC 9312 or T.I. SN29312 and Signetics 8230 for higher speed.
82S31	8-Input Digital Multiplexer		
82S32	8-Input Digital Multiplexer		Replaces Signetics 8231 and Signetics 8232 for higher speed.
82S33	2-Input 4-Bit	7 ns	Replace equivalent non-Schottky parts for higher speed.
82S34	Digital Multiplexers		
82S41	Quad Exclusive OR	7 ns	Replaces 8241 for higher speed.
82S42	Quad Exclusive NOR		Replaces FSC 9386 and 8242 for speed.
82S50	BIN to Octal Decoder	12 ns	Replaces 8250 for higher speed.
82S51	BCD to Decimal Decoder		Replaces 8251 for higher speed.
82S52	BCD to Decimal Decoder		Replaces FSC 9301, T.I. SN29301, and 8252 for higher speed.
82S62	9-Bit Parity Checker/ Generator	17 ns	Replaces 8262 for higher speed and is pin-for-pin replacement for 93S62.
82S66	2-Input 4-Bit Digital	8 ns	Replaces equivalent non-Schottky parts for higher speed.
82S67	Multiplexers and Conditional Complementers		
82S70	4-Bit Shift Register	60 MHz	Replaces 8270, T.I. 74178 and FSC 93178 for higher speed.
82S71	4-Bit Shift Register w/Clear		Replaces 8271, T.I. 72179 and FSC 93179 for higher speed.
82S82	BCD Arithmetic Unit	20 ns	Replaces many MSI and Gate elements. Primarily these are implementations that use multiples of 7483's and Gates.
82S83	BCD Adder		
82S90	Presetable Decade Counter	100 MHz	Replaces 8280, 8290, T.I. 74176, T.I. 74196, FSC 93176, FSC 93196.
82S91	Presetable Binary Counter		Replaces 8281, 8291, T.I. 74177, T.I. 72197, FSC 93177, FSC 93197 for higher speed.

**ABSOLUTE MAXIMUM RATINGS** (Over operating free-air temperature range unless otherwise noted)

The absolute maximum ratings constitute limiting values above which serviceability of the device may be impaired. Provisions should be made in system design and testing to limit voltages in accordance with Table 1.

Input Voltage	+5.5V
Output Voltage (Off-State)	V <sub>CC</sub>
V <sub>CC</sub> (Note 2)	+7.0V
Storage or Junction Temperature Range	
A, B, N, F Packages	-65°C to +175°C
Operating Free-Air Temperature	0°C to 75°C

**NOTES**

1. All devices must be derated at elevated temperatures based on maximum allowable junction temperature. (See maximum storage temperature above and the thermal resistance of the package, given in Section B).
2. Operating V<sub>CC</sub> for the 82S Series is specified at +5V ±5%. None of the Signetics MSI elements will be damaged by supply voltages of 7 volts or less; however, in some of the more complex functions, power dissipation at such voltages could become excessive. It is recommended therefore, that such over-voltages be limited to a maximum of 1 second duration.

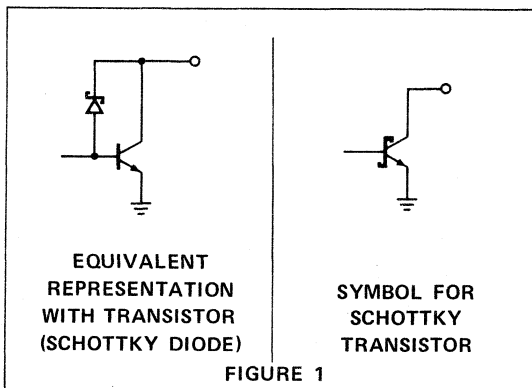
## 82S OPTIMIZED SCHOTTKY MSI

Series 82S optimized Schottky MSI circuits are implemented with Schottky-barrier-Diode (SBD) clamping to achieve ultra-high speed previously only attainable with emitter-coupled logic and in addition low current PNP inputs provide numerous systems advantages. These integrated circuits are directly compatible with other TTL circuits such as the 8000 MSI circuits, 82/82S bipolar memories, 54/74 and 54S/74S as well as MOS/CMOS.

The Schottky barrier diode is a metal-semiconductor diode that is characterized by the absence of minority carriers near the forward biased junction, thus making it possible to switch the diode rapidly since there is no stored charge. Another major difference between the Schottky diode and a p-n junction diode is that the SBD has a lower forward voltage for a given current. SBD clamping from the base to the collector of a switching transistor is shown in Figure 1. The Schottky diode prevents the transistor from saturating and there is no stored charge either in the diode or the transistor. Thus recovery times that contribute significantly to the overall propagation delays experienced in saturated digital-logic design are eliminated.

The Schottky-clamped transistors are formed by using Schottky-barrier-diodes in parallel with the base-collector junction. The SBD is realized physically by depositing metal over the base and N region of the collector forming a metal-silicon diode. The effect of this diode, which has a lower forward voltage than the collector-base junction is to hold the transistor out of saturation by diverting the excess base current. The reduction in stored-charge plus the use of smaller geometries results in a major improvement of switching characteristics.

## SCHOTTKY TRANSISTOR

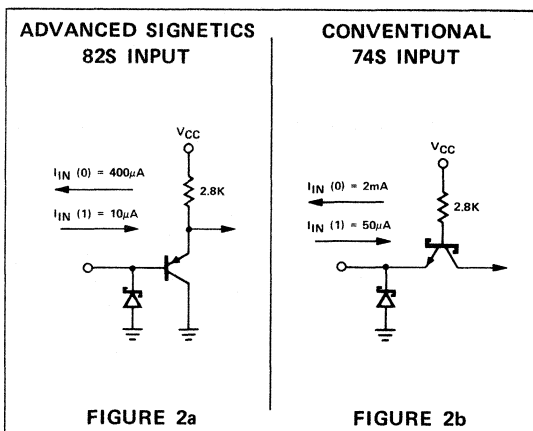


The standard processing approach to charge storage reduction in conventional IC's has been gold doping. Since this is no longer necessary in Schottky circuits, elimination of gold doping has made it possible to use smaller geometries and shallower diffusions for higher speed transistors.

By eliminating gold doping normally employed in conventional TTL processing to reduce storage time, PNP transistors can also be used to advantage by the circuit designers.

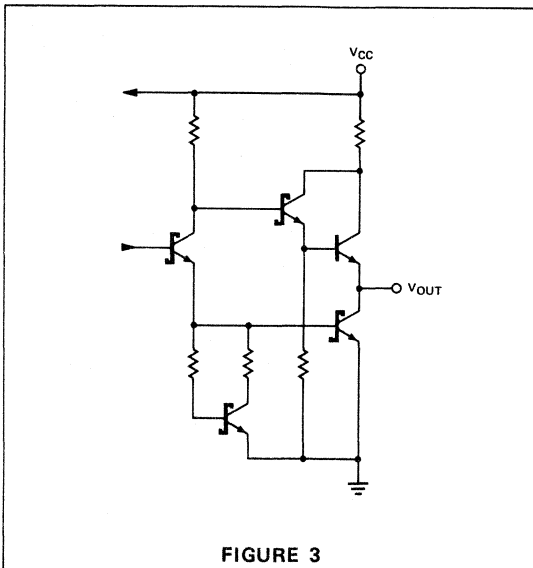
In 82S MSI circuits PNP transistors are used to reduce input loading as illustrated in Figure 2. Maximum low level input current is specified at  $400\mu\text{A}$  which allows the systems' designer to upgrade existing designs without encountering fanout limitations as well as interface with MOS and CMOS.

## INPUT TRANSISTORS COMPARISON



Since the 82S/74S output structure is the same, far more devices can be driven from one output since the 82S input loading is only one-fifth that of standard 74S Schottky inputs. Should a termination resistor be needed when driving long lines in addition to 10 PNP loads, it can be accommodated easily without fan-out reduction.

## 82S/74S OUTPUT STRUCTURE







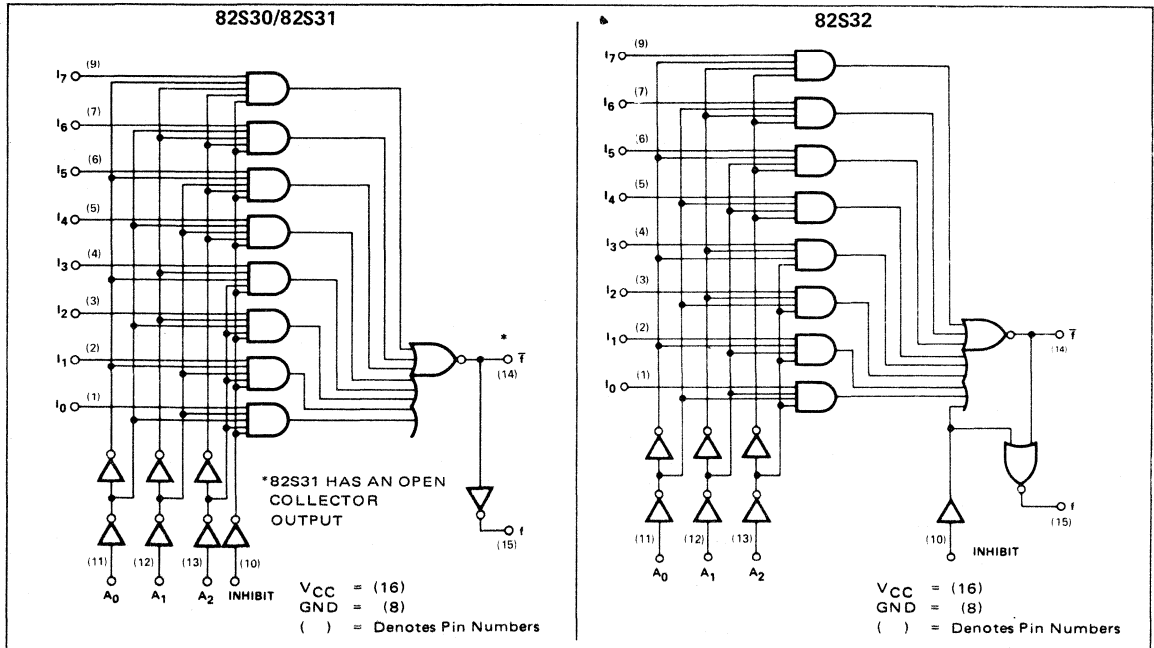
### DESCRIPTION

These 8-Input Digital Multiplexers are the logical equivalent of a single-pole, 8 position switch whose position is specified by a 3-bit input address.

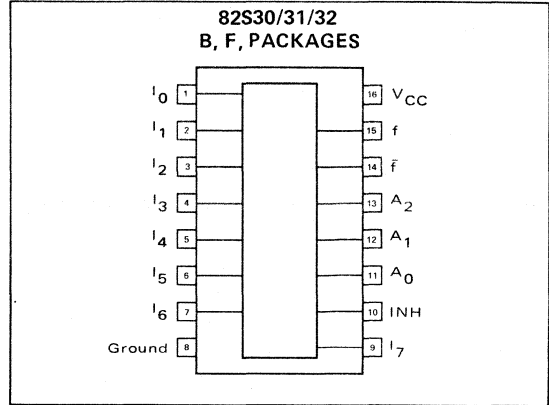
The 82S30 incorporates an INHIBIT input which, when low, allows the one-of-eight inputs selected by the address to appear on the f output and, in complement, on the  $\bar{f}$  output. With the INHIBIT input high, the f output is unconditionally low and the  $\bar{f}$  output is unconditionally high. The 82S31 is a variation of the 82S30 that provides an open collector output f for expansion of input terms.

The 82S32 is similar to the 82S30 except in the effect of the INHIBIT input on the f output. With the INHIBIT low, the selected input appears at the f output and, in complement, on the  $\bar{f}$  output. With the INHIBIT input high, both the f and the  $\bar{f}$  output are unconditionally low.

### LOGIC DIAGRAMS



### PIN CONFIGURATION (Top View)



### FEATURES

- SCHOTTKY-CLAMPED TTL STRUCTURE
- LOW CURRENT PNP INPUTS
- 82S30 REPLACES 9312 FOR HIGHER SPEED
- 82S31 HAS OPEN COLLECTOR OUTPUT
- 82S32 HAS DIRECT OUTPUT INHIBIT

**D.C. ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN	TYP	MAX	UNITS	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	INH	DATA INPUT I <sub>n</sub>	OUTPUTS	
"1" Output Voltage (All outputs except $\bar{f}$ of 82S31)	2.7			V	*	*	*	*		-1.0mA	6,10
"1" Output Leakage Current			250	$\mu$ A	*	*	*	*			
"0" Output Voltage			0.5	V	*	*	*	*		20mA	7,10
"1" Input Current Inputs A <sub>n</sub> , I <sub>n</sub> , I <sub>nh</sub>			10	$\mu$ A	4.5V	4.5V	4.5V	4.5V	4.5V		
"0" Input Current A <sub>n</sub> , I <sub>n</sub> , INH			-400	$\mu$ A	0.5V	0.5V	0.5V	0.5V	0.5V		
Power Consumption/ Supply Current			325/62	mW/mA	4.5V	4.5V	4.5V	4.5V	0V		9,11
Output Short Circuit Current Output $\bar{f}$	-40		-100	mA	0V	0V	0V	0V	4.5V	0V	9
Output $\bar{f}$	-40		-100	mA	0V	0V	0V	0V	0V	0V	9
Input Clamp Voltage	-1.2			V	-18 mA	-18 mA	-18 mA	-18 mA			

\*See Truth Table for logical conditions.

**A.C. ELECTRICAL CHARACTERISTICS** T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Propagation Delay (t <sub>on</sub> , t <sub>off</sub> ) Data, I <sub>n</sub> to $\bar{f}$		7	10	ns	Per Test Table R <sub>L</sub> = 280 $\Omega$ C <sub>L</sub> = 15pF	8
82S30/32		9	12	ns		
82S31		14	17	ns		
Address A <sub>n</sub> to $\bar{f}$		16	19	ns		
82S30/32		6	9	ns		
82S31		12	16	ns		
$\bar{f}$ to $\bar{f}$		14	18	ns		
INH to $\bar{f}$						
82S30/32						
82S31						

NOTES

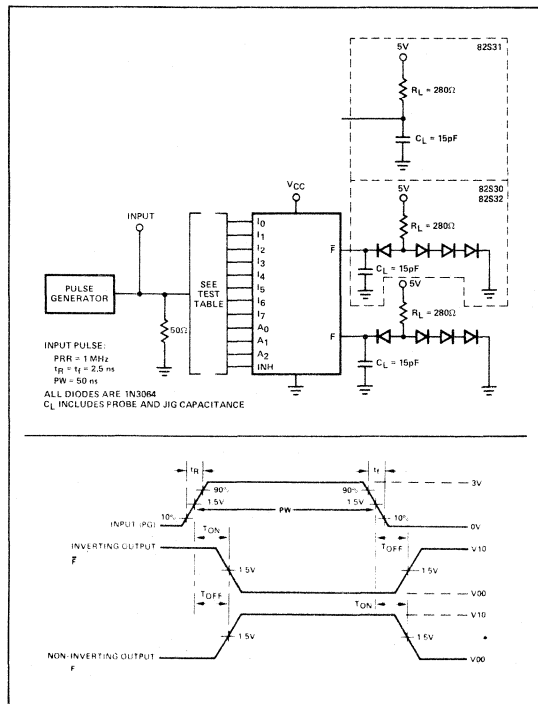
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figures.
- V<sub>CC</sub> = 5.25V.
- By DC tests per the truth table, all inputs have guaranteed thresholds at 0.8V for logical "0" and 2.0V for logical "1".
- All I<sub>n</sub> data inputs are at 0V.

TRUTH TABLE

ADDRESS			DATA INPUT								OUTPUTS			
A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	I <sub>7</sub>	I <sub>6</sub>	I <sub>5</sub>	I <sub>4</sub>	I <sub>3</sub>	I <sub>2</sub>	I <sub>1</sub>	I <sub>0</sub>	INH	f	$\bar{f}$ 82S30/ 31	$\bar{f}$ 82S32
0	0	0	X	X	X	X	X	X	X	1	0	1	0	0
0	0	1	X	X	X	X	X	X	1	X	0	1	0	0
0	1	0	X	X	X	X	X	1	X	X	0	1	0	0
0	1	1	X	X	X	X	1	X	X	X	0	1	0	0
1	0	0	X	X	X	1	X	X	X	X	0	1	0	0
1	0	1	X	X	1	X	X	X	X	X	0	1	0	0
1	1	0	X	1	X	X	X	X	X	X	0	1	0	0
1	1	1	1	X	X	X	X	X	X	X	0	1	0	0
0	0	0	X	X	X	X	X	X	X	0	0	0	1	1
0	0	1	X	X	X	X	X	X	0	X	0	0	1	1
0	1	0	C	X	X	X	X	0	X	X	0	0	1	1
0	1	1	X	X	X	X	0	X	X	X	0	0	1	1
1	0	0	X	X	X	0	X	X	X	X	0	0	1	1
1	0	1	X	X	0	X	X	X	X	X	0	0	1	1
1	1	0	X	0	X	X	X	X	X	X	0	0	1	1
1	1	1	0	X	X	X	X	X	X	X	0	0	1	1
X	X	X	C	X	X	X	X	X	X	X	1	0	1	0

X = don't care

A.C. TEST FIGURE AND WAVEFORMS



TEST TABLE

TEST NO.	INPUTS											OUTPUTS		
	A <sub>0</sub>	A <sub>1</sub>	A <sub>2</sub>	INH	I <sub>0</sub>	I <sub>1</sub>	I <sub>2</sub>	I <sub>3</sub>	I <sub>4</sub>	I <sub>5</sub>	I <sub>6</sub>	I <sub>7</sub>	F	F
1	PG	0	0	0	0	1	0	0	0	0	0	0	T	T
2	0	PG	0	0	0	0	1	0	0	0	0	0	T	
3	0	0	PG	0	0	0	0	1	0	0	0	0	T	
4	0	1	1	PG	0	0	0	0	1	0	0	0	T	
5	1	1	1	0	0	0	0	0	0	0	0	PG	T	

F. "1" = 2.7V "0" = GROUND

NOTE

- AC test jigs must not have any switches.
- AC test jigs must have less than 1/8 inch lead lengths from package pins.

### DIGITAL 8000 SERIES SCHOTTKY TTL/MSI

#### DESCRIPTION

These 2-input, 4-Bit Digital Multiplexers are designed for general purpose high speed data-selection applications.

The 82S33 features non-inverting data paths whereas, the 82S34 features inverting data paths.

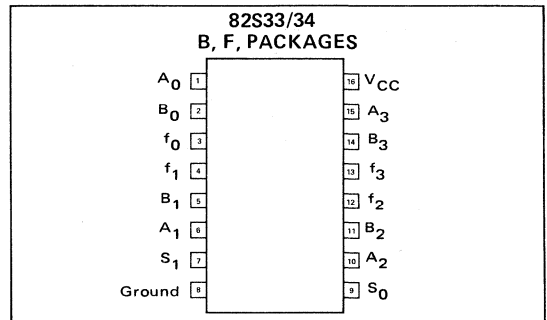
The 82S34 has open collector outputs which permit direct wiring to other open collector outputs (collector logic) to yield "free" four-bit words. As many as forty four-bit words can be multiplexed by using twenty 82S34's in the WIRED-AND mode.

The inhibit state  $S_0 = S_1 = 1$  can be used to facilitate transfer operations in an arithmetic section.

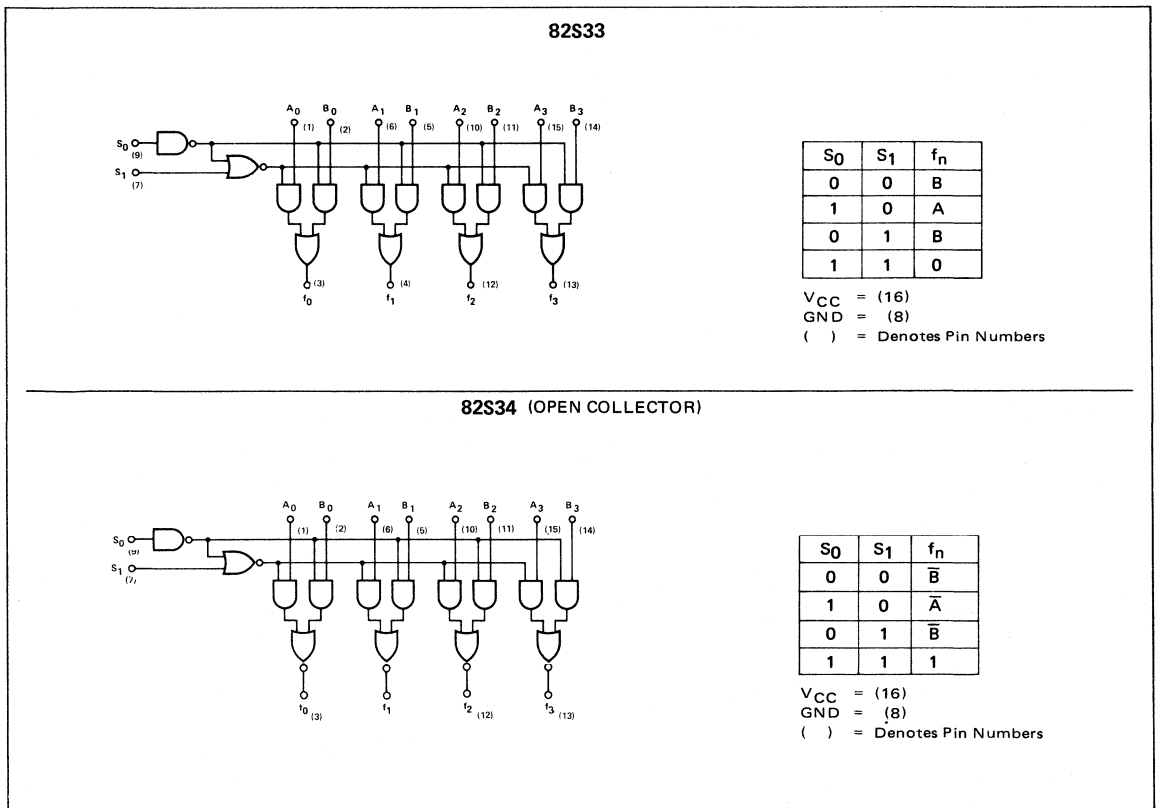
#### FEATURES

- SCHOTTKY-CLAMPED TTL STRUCTURE
- LOW CURRENT PNP INPUTS
- OPEN COLLECTOR OUTPUTS (82S34)
- INHIBIT STATE

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAM



# SIGNETICS 2-INPUT 4-BIT DIGITAL MULTIPLEXER ■ 82S33/82S34

## D.C. ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
	MIN	TYP	MAX	UNITS	INPUTS					
					A <sub>n</sub>	B <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>		
"1" Output Voltage (82S33)	2.7			V	2.0V	2.0V	0.8V	0.8V	-1mA 20mA	6 7
"0" Output Voltage (82S33)			0.5	V	0.8V	2.0V	2.0V	0.8V		
"0" Output Voltage (82S34)			0.5	V	0.8V	2.0V	0.8V	0.8V	20mA	7 9
"1" Output Leakage Current (82S34)			250	μA	2.0V	2.0V	2.0V	2.0V		
"0" Input Current (ALL)			-400	μA	0.5V	0.5V	0.5V	0.5V	0V	10, 11
"1" Input Current (ALL)			10	μA	4.5V	4.5V	4.5V	4.5V		
Output Short Circuit Current (82S33)	-40		-100	mA	5V	5V	0V	0V		
Input Clamp Voltage (ALL)			-1.2	V	-18mA	-18mA	-18mA	-18mA		
Power/Current										
Consumption:										
82S33			305/58	mW/mA		0V		0V		10
82S34			265/50	mW/mA		0V		0V		10

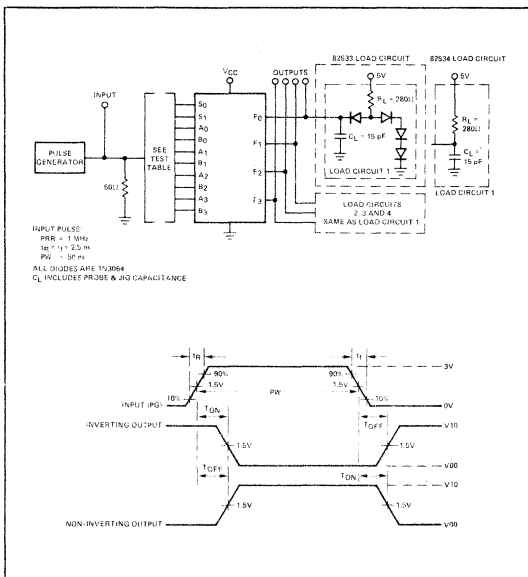
## A.C. ELECTRICAL CHARACTERISTICS T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
82S33/34 Turn-On/Turn-Off Times Data, A <sub>n</sub> , B <sub>n</sub> to f <sub>n</sub>		7	12	ns	Per Test Table R <sub>L</sub> = 280Ω C <sub>L</sub> = 15pF	8
Select, S <sub>0</sub> to f <sub>n</sub>		13	18	ns		
Select, S <sub>1</sub> to f <sub>n</sub>		11	16	ns		

### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Refer to AC Test Figures and Test Table.
- Connect an external 1K ±1% to V<sub>CC</sub> for this test.
- V<sub>CC</sub> = 5.25V.
- Not more than one output should be shorted at a time.

## A.C. TEST FIGURE AND WAVEFORMS



## TEST TABLE

TEST NO.	INPUTS										OUTPUTS			
	S <sub>0</sub>	S <sub>1</sub>	A <sub>0</sub>	B <sub>0</sub>	A <sub>1</sub>	B <sub>1</sub>	A <sub>2</sub>	B <sub>2</sub>	A <sub>3</sub>	B <sub>3</sub>	F <sub>0</sub>	F <sub>1</sub>	F <sub>2</sub>	F <sub>3</sub>
1	PG	0	1	0	1	0	1	0	1	0	T			
2	PG	0	1	0	1	0	1	0	1	0	T	T	T	T
3	PG	0	0	1	0	1	0	1	0	1		T		
4	1	PG	1	0	1	0	1	0	1	0			T	
5	0	0	0	PG	0	0	0	0	0	0	T			
6	0	1	0	0	0	PG	0	0	0	0		T		
7	1	0	0	0	0	0	PG	0	0	0			T	
8	1	0	0	0	0	0	0	0	PG	0				T

"1" = 2.7V "0" = GROUND

### NOTE

- AC test jigs must not have any switches.
- AC test jigs must have less than 1/8 inch lead length from package pins.

### DIGITAL 8000 SERIES SCHOTTKY TTL/MSI

#### DESCRIPTION

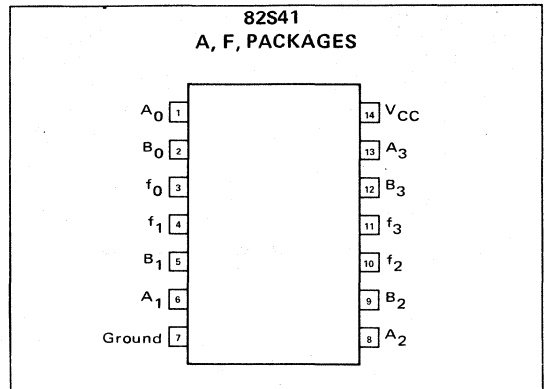
The 82S41 contains four independent gating structures to perform the Exclusive-OR function on two input variables. The output of the 82S41 employs the totem-pole structure characteristic of TTL devices.

#### FEATURES

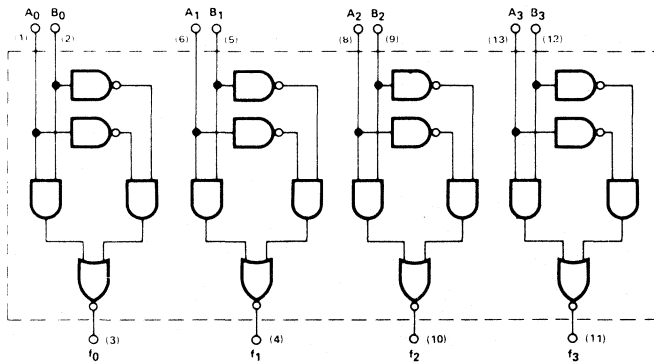
- SCHOTTKY-CLAMPED TTL STRUCTURE
- LOW CURRENT PNP INPUTS
- ULTRA HIGH SPEED

#### LOGIC DIAGRAMS

#### PIN CONFIGURATION (Top View)



#### 82S41 QUAD EXCLUSIVE-OR



A	B	f
0	0	0
1	0	1
0	1	1
1	1	0

V<sub>CC</sub> = (14)  
GND = (7)  
( ) = Denotes Pin Numbers

**D.C. ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP	MAX	UNITS	INPUTS		OUTPUTS	
					A	B		
Output "1" Voltage	2.7			V	2.0V	0.8V	-1mA	7
Output "0" Voltage			0.5	V	2.0V	2.0V	20mA	8
Input "1" Current			10	μA	4.5V	4.5V		11
Input "0" Current			-800	μA	0.5V	0.5V		12
Power/Current Consumption			290/55	mW/mA				13
Output Short Circuit Current	-40		-100	mA		-18mA	0V	13,10
Input Clamp Voltage	-1.2			V	-18mA			

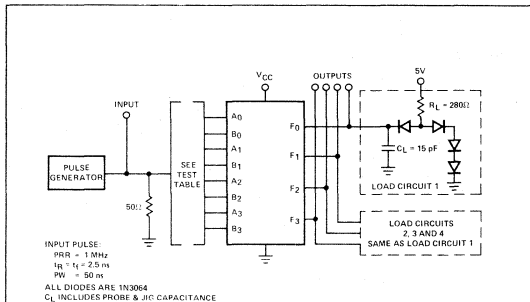
**A.C. ELECTRICAL CHARACTERISTICS**  $T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS		NOTES
	MIN	TYP	MAX	UNITS	Per Test Table		
Turn-On/Turn-Off Times		7	10	ns	$R_L = 280\Omega$	$C_L = 15\text{pF}$	9

**NOTES**

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive NAND logic definition: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Measurements apply to each gate element independently.
7. Output source current is supplied through a resistor to ground.
8. Output sink current is supplied through a resistor to  $V_{CC}$ .
9. Refer to AC Test Figure.
10. Not more than one output should be shorted at a time.
11. A and B are tested separately. When A is 4.5V, B is 0V, and vice versa.
12. A and B are tested separately. When A is 0.4V, B is 5.25V, and vice versa.
13.  $V_{CC} = 5.25\text{V}$ .

**A.C. TEST FIGURE AND WAVEFORMS**



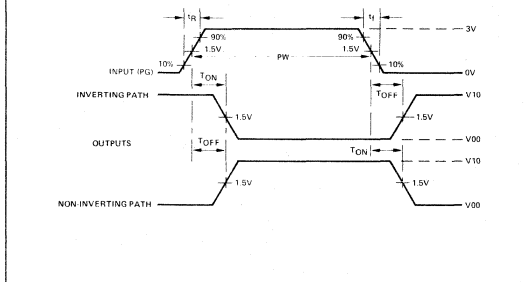
**TEST TABLE**

TEST NO.	INPUTS								OUTPUTS			
	A0	B0	A1	B1	A2	B2	A3	B3	F0	F1	F2	F3
1	0	0	0	PG	0	0	0	0		T		
2	0	PG	0	0	0	0	0	0	T			
3	0	0	0	PG	0	0	0	0		T		
4	0	0	0	0	0	PG	0	0			T	
5	0	0	0	0	0	0	0	0				T
6	PG	0	0	0	0	0	0	0	T			
7	0	0	0	0	0	0	PG	0				T

"1" = 2.7V "0" = GROUND

**NOTE**

1. AC test jigs must not have any switches.
2. AC test jigs must have less than 1/8 inch lead length from package pins.



### DESCRIPTION

The 82S42 contains four independent Exclusive-NOR gates which may be used to implement digital comparison functions. The 82S42 outputs are bare collector to facilitate implementation of multiple-bit comparisons; a 4-bit comparison is made by connecting the outputs of the four independent gates together.

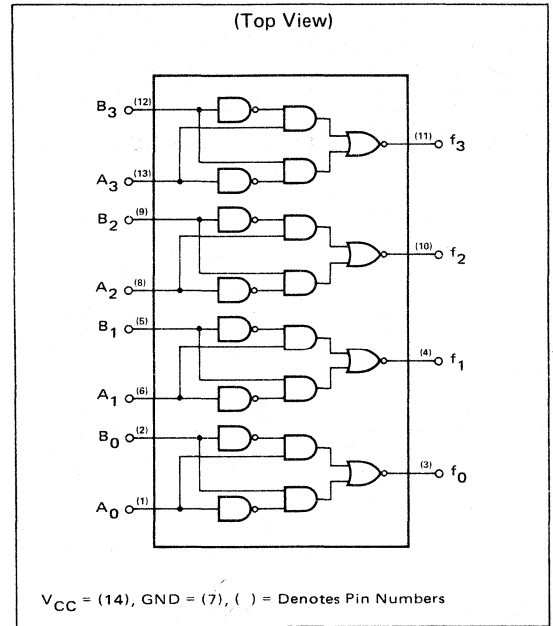
### FEATURES

- SCHOTTKY-CLAMPED TTL STRUCTURE
- LOW CURRENT PNP INPUTS
- OPEN COLLECTOR OUTPUTS

### TRUTH TABLE

A	B	f
0	0	1
1	0	0
0	1	0
1	1	1

### PIN CONFIGURATION & LOGIC DIAGRAM



### D.C. ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS			NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS		OUTPUT	
					A	B		
Output "1" Leakage Current			250	$\mu A$	2.0	2.0	25mA	7
Output "0" Voltage			0.5	V	2.0	0.8		6
Input "1" Current			10	$\mu A$	4.5	4.5V		8
Input "0" Current			-800	$\mu A$	0.4	0.4		9
Power/Current Consumption			326/62	mW/mA	0.4	0.4		10
Input Clamp Voltage	-1.2V				-18mA			
A Input								
B Input						-18mA		

### A.C. ELECTRICAL CHARACTERISTICS $T_A = 25^\circ C$ and $V_{CC} = 5.0V$

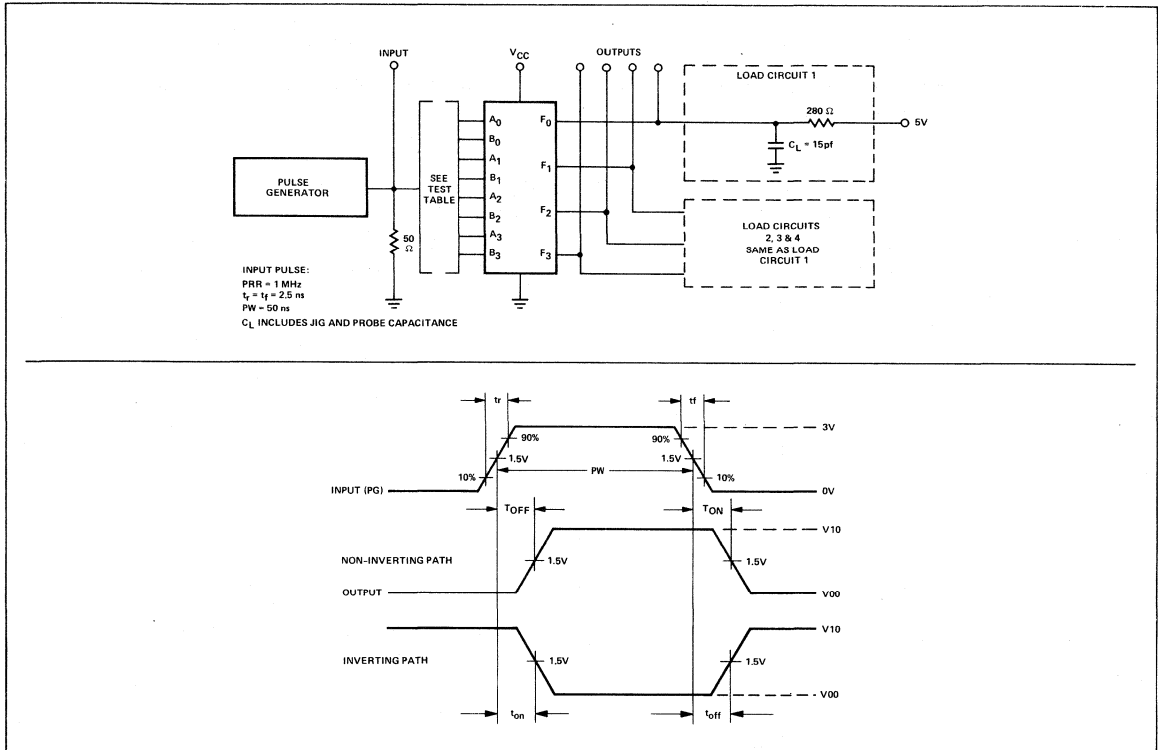
CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Turn On/Turn Off Times		9	14	ns	$R_L = 280\Omega$ $C_L = 15pF$	11



NOTES

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive NAND logic definition: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Output sink current is supplied through a resistor to  $V_{CC}$ .
7. Connect an external 1K  $\pm 1\%$  resistor from  $V_{CC}$  to the output terminal for this test.
8. A and B are tested separately. When A is 4.5V, B is 0V, and vice versa.
9. A and B are tested separately. When A is 0.4V, B is 5.25V, and vice versa.
10.  $V_{CC} = 5.25V$ .
11. Refer to AC Test Figure and Waveform.

A.C. TEST FIGURE AND WAVEFORMS



NOTE

1. A.C. Test Jigs must not have any switches.
2. A.C. Test Jigs must have less than 1/8 inch lead length from package pins.

TEST TABLE

TEST #	INPUTS								OUTPUTS			
	A <sub>0</sub>	B <sub>0</sub>	A <sub>1</sub>	B <sub>1</sub>	A <sub>2</sub>	B <sub>2</sub>	A <sub>3</sub>	B <sub>3</sub>	F <sub>0</sub>	F <sub>1</sub>	F <sub>2</sub>	F <sub>3</sub>
1	0	0	PG	1	0	0	0	0		T		
2	0	0	1	PG	0	0	0	0		T		
3	PG	1	0	0	0	0	0	0	T			
4	1	PG	0	0	0	0	0	0	T			
5	0	0	0	0	1	PG	0	0			T	
6	0	0	0	0	PG	1	0	0			T	
7	0	0	0	0	0	0	1	PG				T
8	0	0	0	0	0	0	PG	1				T

"1" = 2.7V, "0" = GROUND

### DIGITAL 8000 SERIES SCHOTTKY TTL/MSI

#### DESCRIPTION

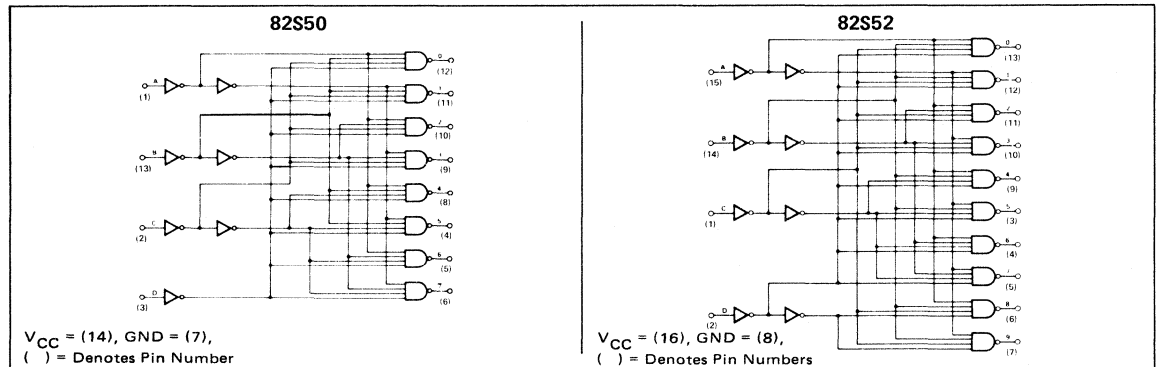
The 82S50 and 82S52 are gate arrays for decoding and code conversion applications.

The 82S50 converts 3 lines of binary input to a one-of-eight output code. The fourth input line (D) is utilized as an inhibit to allow use in larger decoding networks.

The 82S52 converts a 4 line BCD input code (8-4-2-1) to a one-of-ten output code. The 82S52 incorporates blanking of binary codes greater than nine. All outputs being forced high when a binary code greater than nine is applied to the inputs.

The composite Truth Table shows the complete input-output behavior of the 82S50 and 82S52.

#### LOGIC DIAGRAMS



#### TRUTH TABLE

INPUT STATE				OUTPUT STATES									
				82S50							82S52 (Only)		
A	B	C	D	0	1	2	3	4	5	6	7	8	9
0	0	0	0	0	1	1	1	1	1	1	1	1	1
1	0	0	0	0	1	0	1	1	1	1	1	1	1
0	1	0	0	0	1	1	0	1	1	1	1	1	1
1	1	0	0	0	1	1	1	0	1	1	1	1	1
0	0	1	0	0	1	1	1	1	0	1	1	1	1
1	0	1	0	0	1	1	1	1	0	1	1	1	1
0	1	1	0	0	1	1	1	1	1	0	1	1	1
1	1	1	0	0	1	1	1	1	1	1	0	1	1
0	0	0	1	0	1	1	1	1	1	1	1	0	1
1	0	0	1	0	1	1	1	1	1	1	1	1	0
0	1	0	1	0	1	1	1	1	1	1	1	1	1
1	1	0	1	0	1	1	1	1	1	1	1	1	1
0	0	1	1	0	1	1	1	1	1	1	1	1	1
1	0	1	1	0	1	1	1	1	1	1	1	1	1
0	1	1	1	0	1	1	1	1	1	1	1	1	1
1	1	1	1	0	1	1	1	1	1	1	1	1	1

**D.C. ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				A	B	C	D	OUTPUTS	NOTES
	MIN	TYP	MAX	UNITS						
"1" Output Voltage	2.7		0.5	V					-1mA 20mA	6, 10 7, 10
"0" Output Voltage				V						
"1" Input Current			10	μA	4.5V	4.5V	4.5V	4.5V		
"0" Input Current (ALL)			-400	μA	0.5V	0.5V	0.5V	0.5V		
Power/Current Consumption (82S50 Only)			380/72	mW/mA	4.5V	4.5V	4.5V	0V		11
(82S52 Only)			450/85	mW/mA						11
Input Clamp Voltage			-1.2	V	-18mA	-18mA	-18mA	-18mA		
Output Short Circuit Current (ALL)	-40		-100	mA	4.0V	4.0V	4.0V	4.0V	0V	9,11

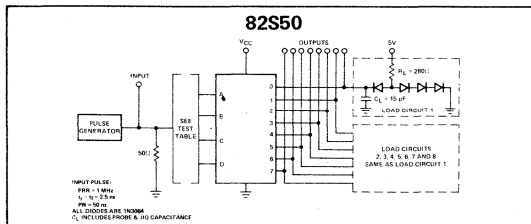
**A.C. ELECTRICAL CHARACTERISTICS** T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				A	B	C	D	OUTPUTS	NOTES
	MIN	TYP	MAX	UNITS						
Turn-on Delay t <sub>on</sub>		12	16	ns						8
Turn-off Delay t <sub>off</sub>		12	16	ns						8

**NOTES**

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Output source current is supplied through a resistor to ground.
7. Output sink current is supplied through a resistor to V<sub>CC</sub>.
8. Refer to AC test Figure.
9. Not more than one output should be shorted at a time.
10. Inputs for "1" and "0" output voltage test is per TRUTH table with threshold levels of 0.8V for logical "0" and 2.0V for logical "1".
11. V<sub>CC</sub> = 5.25V.

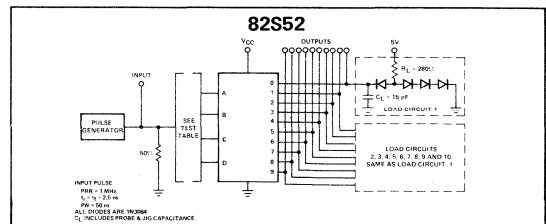
**A.C. TEST FIGURE AND TEST TABLE**



TEST NO.	INPUTS				OUTPUTS							
	A	B	C	D	0	1	2	3	4	5	6	7
1	1	1	PG	0								T
2	1	1	PG	0				T				T
3	PG	1	0	0			T	T				
4	0	PG	1	0				T	T			
5	0	0	0	PG	T							
6	1	0	PG	0		T						T

"1" = 2.7V "0" = Ground

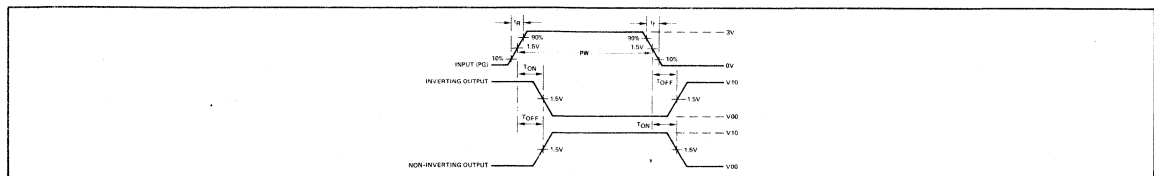
**A.C. TEST FIGURE AND TEST TABLE**



TEST NO.	INPUTS				OUTPUTS									
	A	B	C	D	0	1	2	3	4	5	6	7	8	9
1	0	0	PG	0						T				
2	PG	1	0	0				T	T					
3	0	0	0	PG	T									T
4	1	0	PG	0		T								
5	1	PG	0	1										T
6	PG	1	1	0										

"1" = 2.7V "0" = Ground

**WAVEFORMS**



**NOTE**

1. AC Test Jigs Must Not Have Any Switches.
2. AC Test Jigs Must Have Less Than 1/8 Inch Lead Length From Package Pins.

### DESCRIPTION

The 82S62 9-Input Parity Generator/Parity Checker is an ultra high speed Schottky MSI device commonly used to detect errors in data transmission or in data retrieval. Two outputs (EVEN and ODD) are provided for versatility. An INHIBIT input is provided to disable both outputs of the 82S62. (A logic 1 on the INHIBIT input forces both outputs to a logic 0.)

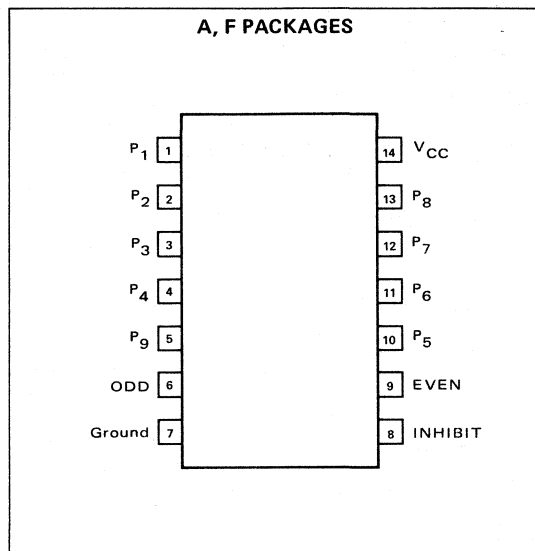
When used as a Parity Generator, the 82S62 supplies a parity bit which is transmitted together with the data word.

At the receiving end, the 82S62 acts as a Parity Checker and indicates that data has been received correctly or that an error has been detected.

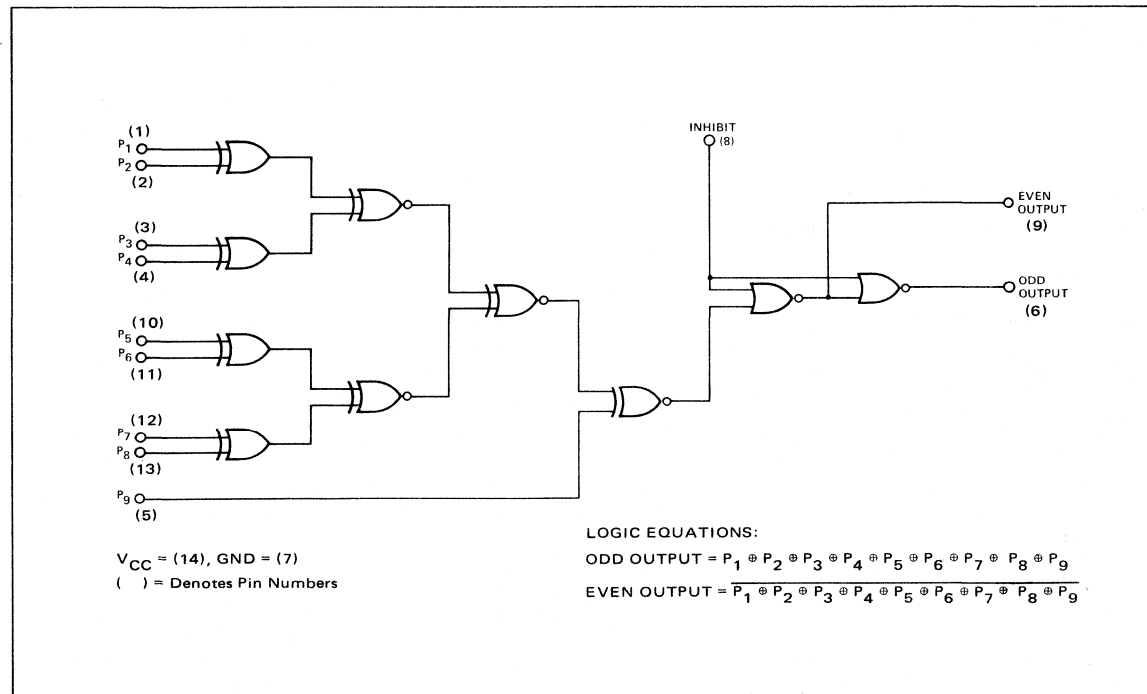
### FEATURES

- SCHOTTKY-CLAMPED TTL STRUCTURE
- LOW CURRENT PNP INPUTS
- EVEN/ODD PARITY OUTPUTS
- INHIBIT INPUT
- PIN-COMPATIBLE WITH 93S62

### PIN CONFIGURATION (Top View)



### LOGIC DIAGRAM



D.C. ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS	INHIBIT	OUTPUTS UNDER TEST	NOTES
	MIN	TYP	MAX	UNITS	DATA INPUT UNDER TEST			
"1" Output Voltage								
Even	2.7			V	0V	.8V	-1mA	6
Odd	2.7			V	2.0V	.8V	-1mA	6
"0" Output Voltage								
Even			0.5	V	2.0V	.8V	20mA	7
Odd			0.5	V	0V	.8V	20mA	7
"0" Input Current								
Data Inputs P <sub>1</sub> -P <sub>8</sub>			-800	μA	0.5V			
Data Input P <sub>9</sub>			-1.2	mA	0.5V			
Inhibit			-800	μA		0.5V		
"1" Input Current								
Data Inputs			10	μA	4.5V			
Inhibit			10	μA		4.5V		
Power/Current Consumption			355/67	mW/mA				9
Output Short Circuit Current								
Even	-40		-100	mA	0V	0V	0V	9,10
Odd	-40		-100	mA	4.5V	0V	0V	9,10

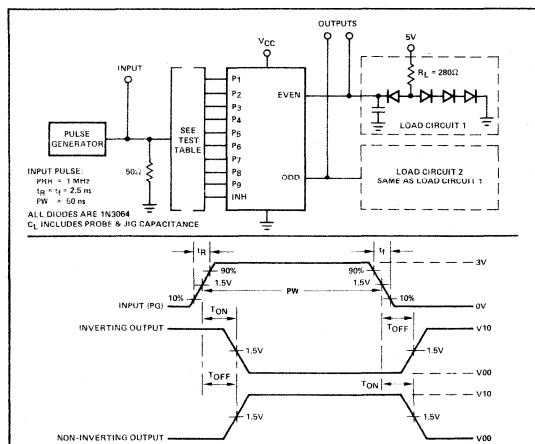
A.C. ELECTRICAL CHARACTERISTICS T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Turn-on/Turn-off Times						
P <sub>1</sub> - P <sub>8</sub> to Even		17	23	ns	Per Test Table R <sub>L</sub> = 280Ω C <sub>L</sub> = 15pF	8
P <sub>1</sub> - P <sub>8</sub> to Odd		18	28	ns		
P <sub>9</sub> to Even		7	12	ns		
P <sub>9</sub> to Odd		12	18	ns		
Inhibit to Even		7	9	ns		
Inhibit to Odd		6	9	ns		

NOTES

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive logic: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Output source current is supplied through a resistor to ground.
7. Output sink current is supplied through a resistor to V<sub>CC</sub>.
8. Refer to AC Test Figure.
9. V<sub>CC</sub> = 5.25V.
10. Not more than one output should be shorted at a time.

A.C. TEST FIGURE AND WAVEFORMS



TEST TABLE

TEST NO.	INPUTS									OUTPUTS		
	P1	P2	P3	P4	P5	P6	P7	P8	P9	INH	EVEN	ODD
1	PG	0	0	0	0	0	0	0	0	0	T	T
2	0	0	PG	0	0	0	0	0	0	0	T	T
3	0	0	0	0	PG	0	0	0	0	0	T	T
4	0	0	0	0	0	0	PG	0	0	0	T	T
5	0	0	0	0	0	0	0	0	PG	0	T	T
6	0	0	0	0	0	0	0	0	0	PG	T	
7	0	0	0	0	0	0	0	0	0	1	PG	T

"1" = 2.7V "0" = Ground "T" = Test

NOTE:

1. AC Test Jig Must Not Have Any Switches.
2. AC Test Jigs Must Have Less Than 1/8 Inch Lead Length From Package Pins.

### DIGITAL 8000 SERIES SCHOTTKY TTL/MSI

#### DESCRIPTION

The 82S66/82S67 2-Input, 4-Bit Digital Multiplexers are ultra high speed Schottky MSI circuits. The 82S67 features a bare-collector output to allow expansion with other devices (wired and collector logic).

The multiplexers are intended for use in conjunction with adders, registers and in other parallel data handling applications.

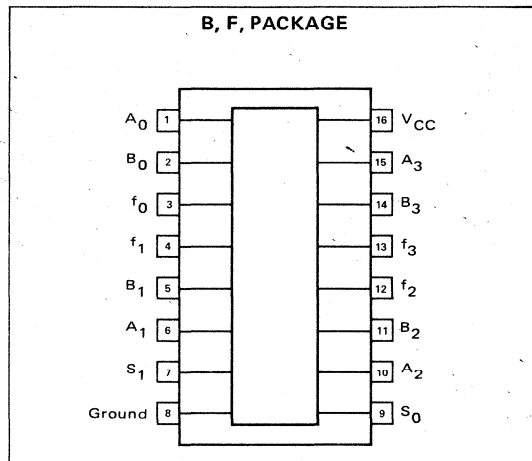
The multiplexers are able to choose from two different input sources, each containing 4 bits:  $A = (A_0, A_1, A_2, A_3)$ ,  $B = (B_0, B_1, B_2, B_3)$ . The selection is controlled by the input  $S_0$ , while the second control input,  $S_1$ , is held at zero.

For conditional complementing, the two inputs ( $A_n, B_n$ ) are tied together to form the function TRUE/COMPLEMENT, which is needed in conjunction with adder elements to perform ADDITION/SUBTRACTION. Further, the inhibit state  $S_0 = S_1 = 1$  can be used to facilitate transfer operations in an arithmetic section.

#### FEATURES

- SCHOTTKY-CLAMPED TTL STRUCTURE
- LOW CURRENT PNP INPUTS
- OPEN COLLECTOR OUTPUTS (82S67)
- INHIBIT STATE

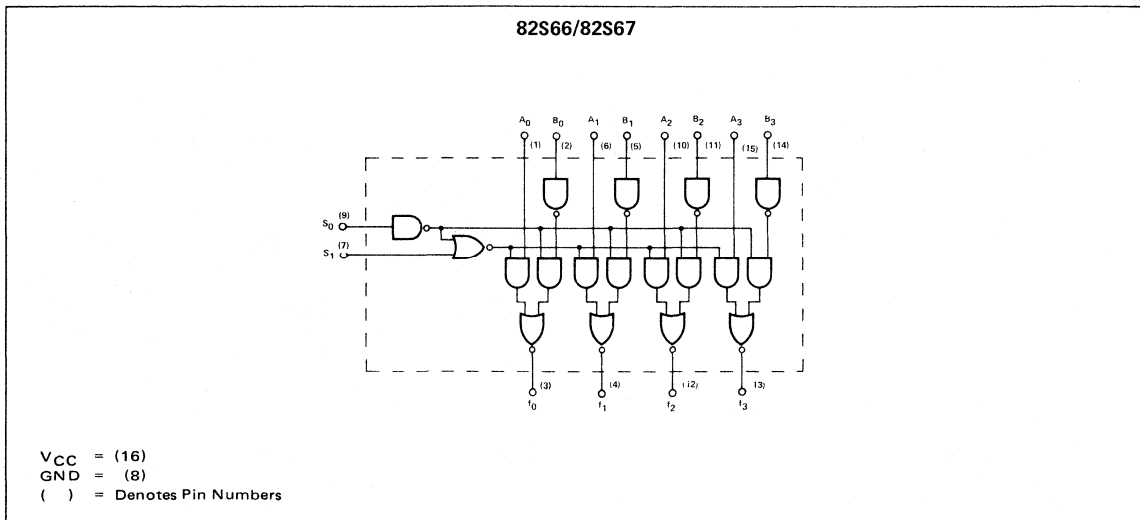
#### PIN CONFIGURATION (Top View)



#### TRUTH TABLE

SELECT LINES		OUTPUTS
$S_0$	$S_1$	$f_n (0, 1, 2, 3)$
0	0	$B_n$
0	1	$\bar{B}_n$
1	0	$A_n$
1	1	1

#### LOGIC DIAGRAM



**D.C. ELECTRICAL CHARACTERISTICS** Over Recommended Operating Temperature and Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS				OUTPUTS	NOTES
	MIN	TYP	MAX	UNITS	A <sub>n</sub>	B <sub>n</sub>	S <sub>0</sub>	S <sub>1</sub>		
"1" Output Voltage (82S66)	2.7	3.5		V	0.8V	2.0V	0.8V	0.8V	-1mA	7
"0" Output Voltage			0.5	V	2.0V	2.0V	2.0V	0.8V	20mA	8
"1" Output Leakage Current (82S67)			250	μA	0.8V	2.0V	2.0V	0.8V	5.5V	
"0" Input Current										
A <sub>n</sub> , B <sub>n</sub>			-400	μA	0.5V	0.5V	0V	0V		
S <sub>0</sub> , S <sub>1</sub>			-400	μA			0.5V	0.5V		
"1" Input Current										
A <sub>n</sub> , B <sub>n</sub>			10	μA	4.5V	4.5V		2.0V		
S <sub>0</sub> , S <sub>1</sub>			10	μA			4.5V	4.5V		
Output Short Circuit Current (82S66)				mA						10,11
Power/Current Consumption			365/69	mW/mA	4.5V	0V	4.5V	0V		10

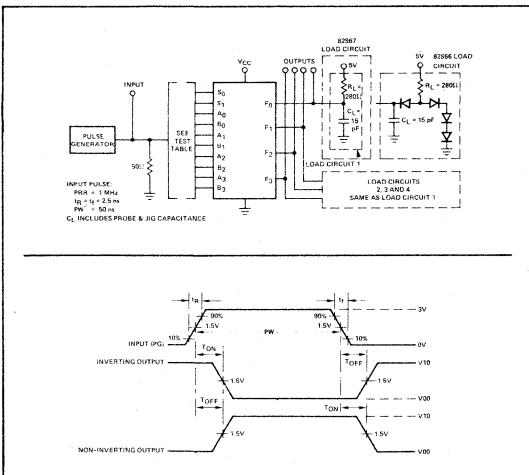
**A.C. ELECTRICAL CHARACTERISTICS** T<sub>A</sub> = 25°C and V<sub>CC</sub> = 5.0V

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Turn-on/Turn-off Times (82S66)					Per Test Table R <sub>L</sub> = 280Ω C <sub>L</sub> = 15pF	9
Select, S <sub>1</sub> to f <sub>n</sub>		10	15	ns		
Select, S <sub>0</sub> to f <sub>n</sub>		12	18	ns		
Data, A <sub>n</sub> to f <sub>n</sub>		5	10	ns		
Data, B <sub>n</sub> to f <sub>n</sub>		8	12	ns		
Propagation Delay (82S67)						
Select, S <sub>1</sub> to f <sub>n</sub>		13	18	ns		
Select, S <sub>0</sub> to f <sub>n</sub>		15	20	ns		
Data, A <sub>n</sub> to f <sub>n</sub>		8	12	ns		
Data, B <sub>n</sub> to f <sub>n</sub>		10	15	ns		

**NOTES**

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive NAND logic definition: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Measurements apply to each gate element independently.
7. Output source current is supplied through a resistor to ground.
8. Output sink current is supplied through a resistor to V<sub>CC</sub>.
9. Refer to AC Test Figure.
10. V<sub>CC</sub> = 5.25V
11. Not more than one output should be shorted at a time.

**A.C. TEST FIGURE AND WAVEFORMS**



**TEST TABLE**

TEST NO.	INPUTS									OUTPUTS				
	S <sub>0</sub>	S <sub>1</sub>	A <sub>0</sub>	B <sub>0</sub>	A <sub>1</sub>	B <sub>1</sub>	A <sub>2</sub>	B <sub>2</sub>	A <sub>3</sub>	B <sub>3</sub>	F <sub>0</sub>	F <sub>1</sub>	F <sub>2</sub>	F <sub>3</sub>
1	1	PG	1	1	1	1	1	1	1	1	T			
2	1	PG	1	1	1	1	1	1	1	1	T	T	T	T
3	PG	0	1	1	1	1	1	1	1	1	T	T		T
4	0	0	0	0	0	PG	0	0	0	0			T	
5	0	0	0	0	0	0	0	PG	0	0				T
6	1	0	PG	1	0	1	0	1	0	1	T			
7	1	0	0	1	0	1	0	1	PG	1				T

"1" = 2.7V "0" = Output

**NOTE**

1. AC Test Jigs Must Not Have Any Switches.
2. AC Test Jigs Must Have Less Than 1/8 Inch Lead Length From Package Pins.

### PRELIMINARY SPECIFICATIONS

### DIGITAL 8000 SERIES SCHOTTKY TTL/MSI

#### DESCRIPTION

The 82S70 and 82S71 are high speed shift registers with both serial and parallel data entry capability and parallel outputs. In addition to the functions available from the 82S70, the 82S71 provides an active low direct reset ( $R_D$ ) input and a complementary output ( $D_{OUT}$ ) of the D flip-flop.

These registers have three distinct modes of operation which are determined by the logic levels on the shift and load inputs in accordance with the functions table. With both the load and shift inputs in the logical "0" state, the registers are in the hold-mode and the systems clock may be left free running without changing the contents of the registers. Parallel loading or serial shift is accomplished on the falling edge of the clock when the shift and load inputs are conditioned as shown in the function table. These shift registers are fully compatible with other TTL, DTL and MSI logic families. All inputs are buffered with low current PNP-inputs and have input-clamping diodes to simplify systems design.

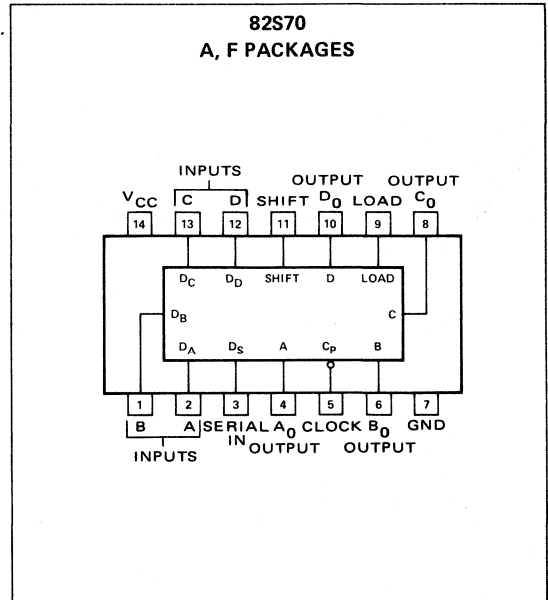
#### FEATURES

- PARALLEL OUTPUTS
- THREE OPERATING MODES  
SYNCHRONOUS PARALLEL LOAD  
RIGHT SHIFT  
HOLD (DO NOTHING)
- NEGATIVE EDGE TRIGGERED CLOCK
- DIRECT OVERRIDING CLEAR (82S71 ONLY)
- DC COUPLED MASTER SLAVE DESIGN
- LOW CURRENT PNP INPUTS
- REPLACES 74178/74179 FOR HIGHER SPEED
- TYPICAL CLOCK FREQUENCY 60 MHz

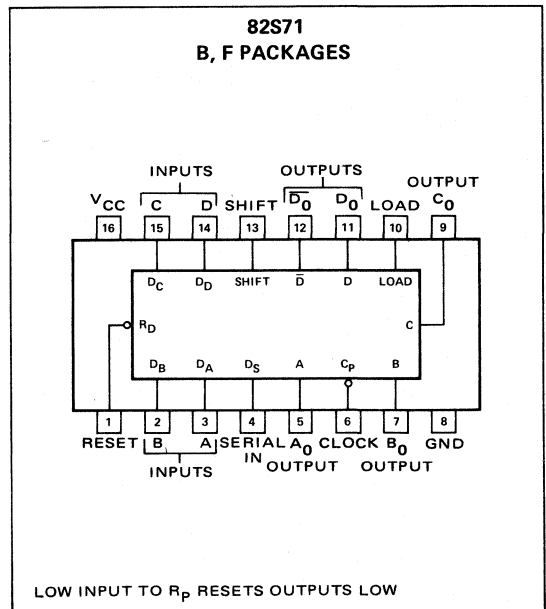
#### FUNCTION TABLE

CONTROL INPUTS		OPERATING MODE
LOAD	SHIFT	
0	0	HOLD
1	0	PARALLEL LOAD
X	1	SHIFT RIGHT ( $Q_A \rightarrow Q_D$ )

#### PIN CONFIGURATION (Top View)



#### PIN CONFIGURATION (Top View)





**D. C. ELECTRICAL CHARACTERISTICS**  $V_{CC} = 5V \pm 5\%$ ,  $T_A = 0^\circ C$  TO  $75^\circ C$

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES
	MIN.	TYP.	MAX.	UNITS	LOAD	SHIFT	DATA INPUTS	CLOCK	RESET 82S71	OUTPUTS	
"1" Output Voltage	2.7	3.5		V	2.0V	0.8V	2.0V	Pulse	2.0V	1.0mA	6
"0" Output Voltage			0.5	V	2.0V	0.8V	0.8V	Pulse	2.0V	20mA	7
"0" Input Current											
Load		-100	-400	$\mu A$	0.5V						
Shift		-150	-800	$\mu A$		0.5V	0.5V				
Data Inputs		-100	-400	$\mu A$			0.5V				
Clock		-100	-400	$\mu A$				0.5V			
Reset (82S71 only)		-150	-800	$\mu A$					0.5V		
"1" Input Current											
Load			10	$\mu A$	4.5V						
Shift			10	$\mu A$		4.5V					
Data Inputs			10	$\mu A$			4.5V				
Clock			10	$\mu A$				4.5V			
Reset (82S71 only)			10	$\mu A$					4.5V		
Input Voltage Rating (All Inputs)	5.5			V	1mA	1mA	1mA	1mA	1mA		
Input Clamp Voltage (All Inputs)			-1.2	V	18mA	18mA	18mA	18mA	18mA		
Power/Current Consumption		315 65	473 90	mW mA							9

**A.C. ELECTRICAL CHARACTERISTICS**  $T_A = 25^\circ C$ ,  $V_{CC} = 5.0V$

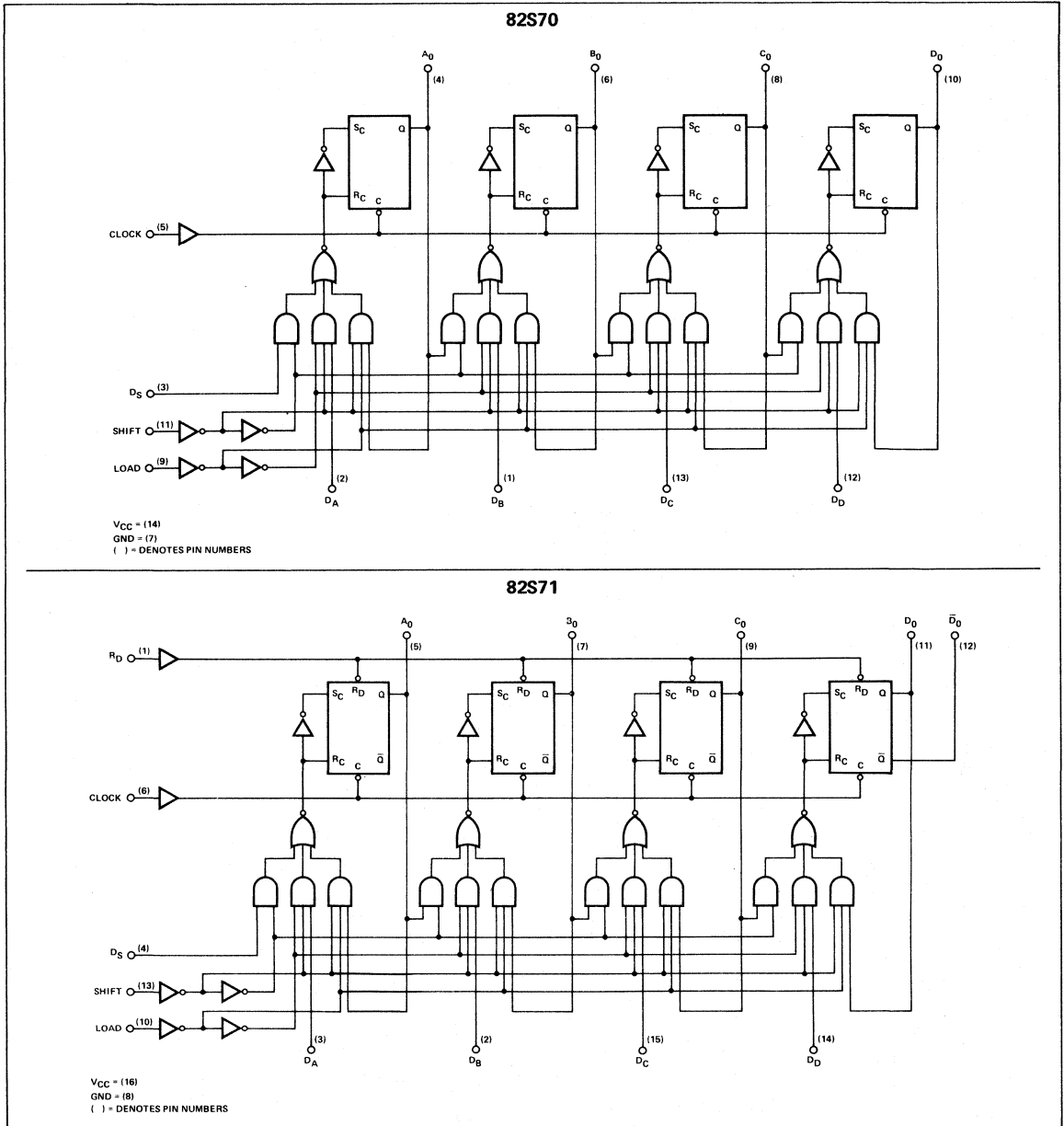
CHARACTERISTICS	LIMITS			UNITS	TEST CONDITIONS
	MIN.	TYP.	MAX.		
Turn-On delay, $t_{ON}$ (Clock to Output)		11	20	ns	SEE AC TEST FIGURE AND WAVEFORMS $C_L = 15 \text{ pF}$ , $R_L = 280\Omega$
Turn-Off Delay, $t_{OFF}$ (Clock to Output)		11	20	ns	
Turn-On Delay, $t_{ON}$ (Reset to Output)		11	16	ns	
Turn-Off Delay, $t_{OFF}$ (Reset to $\overline{Q}_D$ , 82S71)		11	16	ns	
Clock "1" Interval, $t_W$ CLOCK	8			ns	
Transfer Rate	40	60		MHz	
Setup Time, $t_{SETUP}$ Shift/Load		3	6	ns	
Data		1	3	ns	
Hold Time, $t_{HOLD}$ Shift/Load		-2	0	ns	
Data		0	2	ns	
Reset Release Time $t_{RELEASE}$ (82S71 only)		7	10	ns	
Reset Pulse Width $t_W$ RESET (82S71 only)	9	6		ns	

# SIGNETICS HIGH SPEED 4-BIT SHIFT REGISTERS ■ 82S70/82S71

## NOTES

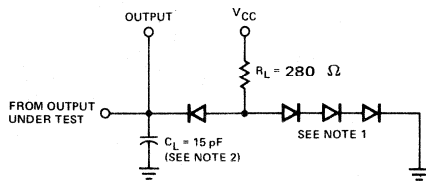
1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive logic definition: "UP" Level = "1", "DOWN" Level "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
6. Output source current is supplied through a resistor to ground.
7. Output sink current is supplied through a resistor to  $V_{CC}$ .
8.  $V_{CC} = 5.25$  volts.

## LOGIC DIAGRAMS

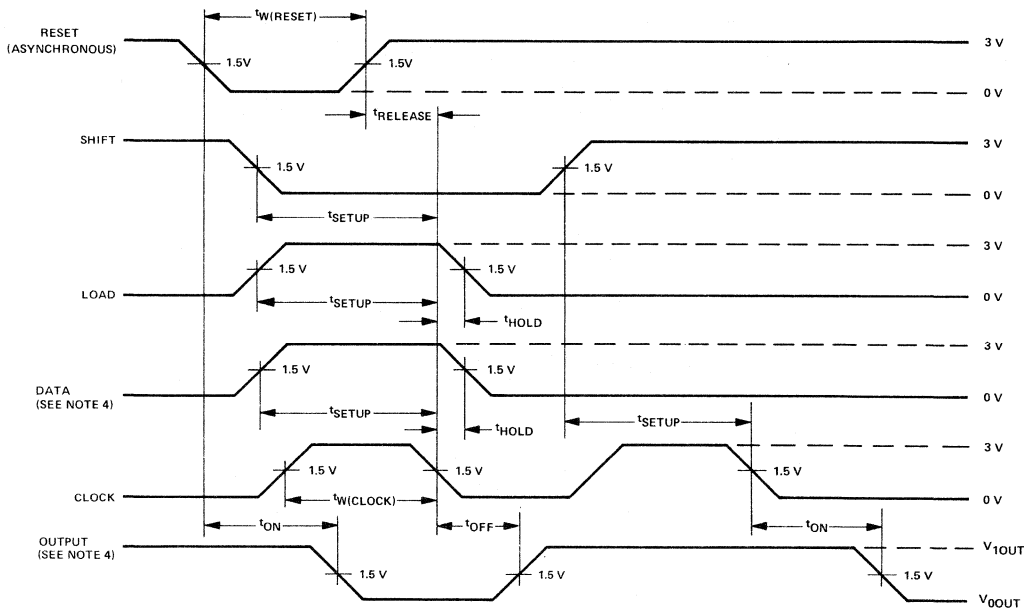


A.C. TEST FIGURE AND WAVEFORMS

LOAD CIRCUIT



VOLTAGE WAVEFORMS



NOTES

1. All diodes are 1N3064.
2.  $C_L$  includes Jig and Probe Capacitance
3. Input pulses are supplied by pulse generators having  $Z_{\text{OUT}} = 50 \Omega$  and the following characteristics:

CLOCK INPUT PULSE

$t_r = t_f = 2.5 \text{ ns}$  (10% to 90%)  
 Pulse amplitude = 3V  
 PRR ( $t_{\text{on}}, t_{\text{off}}$ ) = 1 MHz  
 $t_W$  ( $t_{\text{on}}, t_{\text{off}}$ ) = 50 ns  
 PRR (Max. Freq.) = 40 MHz

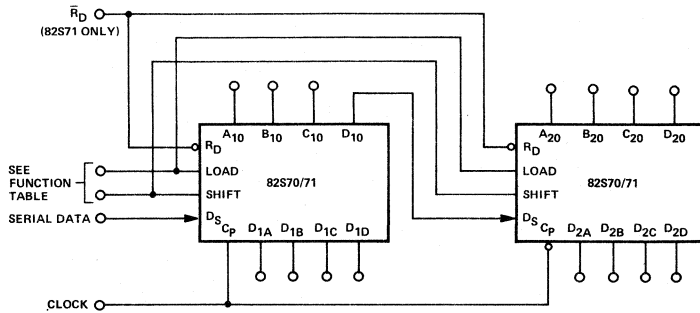
SHIFT/LOAD AND DATA INPUT PULSE

$t_r = t_f = 2.5 \text{ ns}$  (10% to 90%)  
 Pulse amplitude = 3V  
 PRR =  $\frac{1}{2}$  of Clock Freq.  
 $t_W = 50\%$  Duty Cycle

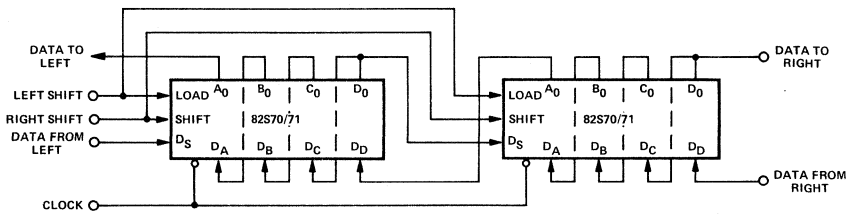
4. Data input and output are any related pair. Serial and other data inputs are at ground. The serial input is tested with the A output when in the shift mode.

TYPICAL APPLICATIONS

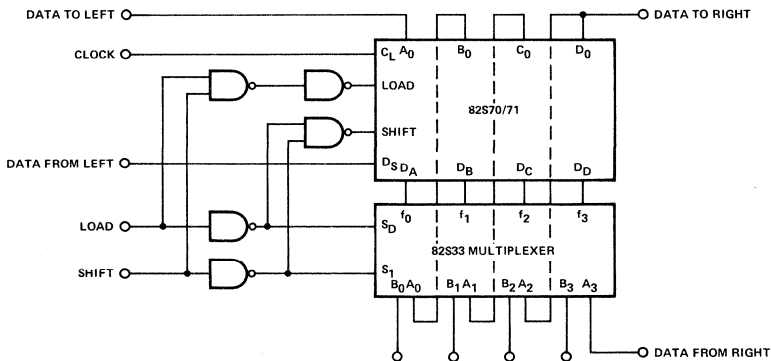
8-BIT RIGHT SHIFT REGISTER WITH SERIAL/PARALLEL ENTRY



CASCADING LEFT-RIGHT SHIFT REGISTERS



SHIFT-RIGHT/SHIFT-LEFT/PARALLEL ENTRY SHIFT REGISTER



LOAD	SHIFT	FUNCTION
0	0	Hold
0	1	Shift Left
1	0	Parallel Load
1	1	Shift Right

PACKAGE COUNT:	1 - 82S70 or 82S71
	1 - 82S33 MULTIPLEXER
	1/2 - 74S00
	1/2 - 74S04

### DESCRIPTION

The 82S82 binary coded (BCD) arithmetic unit is a high speed Schottky MSI circuit with lookahead carry/borrow that has been designed for easy systems usage. Depending on the state of the add/subtract control line, the unit produces the BCD sum or difference of two decimal numbers presented to the BCD inputs in the 8-4-2-1 weighted BCD format. A comparison output (A=B) is provided as well. When in the subtract mode, this output indicates if two BCD numbers are equal and its open collector feature allows easy comparison of several decades.

### FEATURES

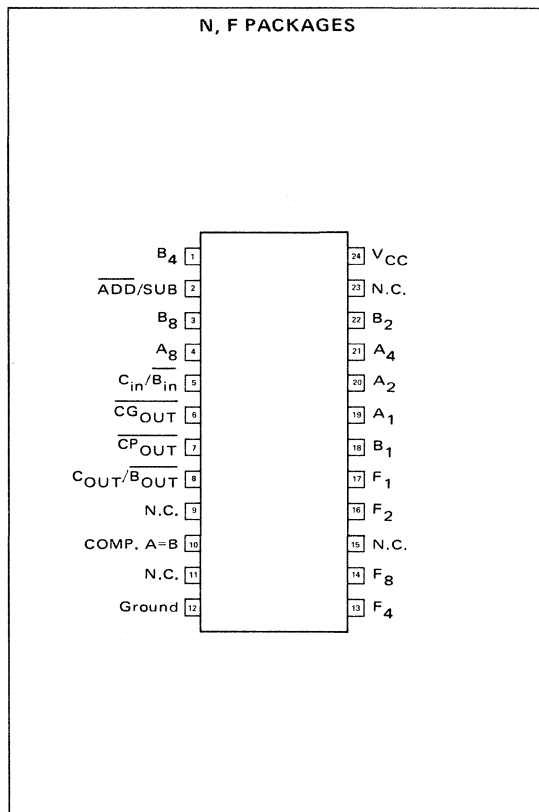
- SCHOTTKY DESIGN FOR HIGH SPEED
- LOW CURRENT PNP INPUTS
- ADDS AND SUBTRACTS BCD NUMBERS
- CONVERTS BINARY TO BCD
- COMPARISON OUTPUT (OPEN COLLECTOR)
- INTERNAL LOOK-AHEAD CARRY/BORROW
- FAST LOOK-AHEAD CARRY/BORROW OUTPUTS
- RIPPLE CARRY/BORROW OUTPUT
- EASY ARRAY EXPANSION
- LOW POWER/CURRENT CONSUMPTION

### 82S82

#### BCD ARITHMETIC UNIT PIN DESIGNATION

Pin Designation	Pin Nos.	Function
A <sub>8</sub> , A <sub>4</sub> , A <sub>2</sub> , A <sub>1</sub>	4, 21, 20, 19	BCD Inputs Word A Weighted (8-4-2-1)
B <sub>8</sub> , B <sub>4</sub> , B <sub>2</sub> , B <sub>1</sub>	3, 1, 22, 18	BCD Inputs Word B Weighted (8-4-2-1)
F <sub>8</sub> , F <sub>4</sub> , F <sub>2</sub> , F <sub>1</sub>	14, 13, 16, 17	BCD Sum/Difference Outputs Weighted (8-4-2-1)
Add/Subtract	2	Add = Logic "0" Subtract = Logic "1"
C <sub>in</sub> /B <sub>in</sub>	5	Carry/Borrow Input
C <sub>out</sub> /B <sub>out</sub>	8	Carry/Borrow Output
CG Out	6	Carry Generate Output (Active Low)
Cp Out	7	Carry Propagate Output (Active Low)
Compare (A=B)	10	Compare Output (Open Collector)
V <sub>CC</sub>	24	Supply Voltage
GND	12	Ground

### PIN CONFIGURATION (Top View)



### TRUTH TABLE

DECIMAL EQUIVALENT	BCD CODE			
	8	4	2	1
0	0	0	0	0
1	0	0	0	1
2	0	0	1	0
3	0	0	1	1
4	0	1	0	0
5	0	1	0	1
6	0	1	1	0
7	0	1	1	1
8	1	0	0	0
9	1	0	0	1

## SIGNETICS 4-BIT BCD ARITHMETIC UNIT ■ 82S82

The 82S82 BCD arithmetic unit has been designed such that input and output logic levels including the carry/borrow are in their true logic form. Compared to multichip hardware solutions previously at the designer's disposal, the 82S82 arithmetic unit generates the BCD carry/borrow terms internally in the look-ahead mode and does BCD arithmetic directly. For more than one BCD decade the carry/borrow term may ripple between 82S82's. For ultra fast BCD arithmetic operations the Signetics 74182 fast-carry extender may be used together with the 82S82's. The 74182 suitably combines the 82S82's active low carry generate ( $\overline{C_gOUT}$ ) and carry propagate ( $\overline{C_pOUT}$ ) terms for complete look-ahead carry between decades.

When the  $\overline{ADD/SUBTRACT}$  control input is low, BCD addition is performed ( $A + B + C_{in} = F$ ). Input codes above 9 to either the  $A_N$  or  $B_N$  inputs are not defined to give valid output sums except for the special case of binary to BCD conversion. In the normal BCD addition mode the F outputs show true BCD results and an active high carryout signal results for sums greater than 9.

For subtraction the  $\overline{ADD/SUBTRACT}$  control input must be high. Internally subtraction is performed by 9's complement addition yielding the difference ( $A - B - 1 = F$ ) of two BCD numbers when the  $C_{in}/\overline{B_{in}}$  input is low. If the  $C_{in}/\overline{B_{in}}$  is high during subtraction, the absence of a borrow in signal gives  $A-B=F$ . For  $A \geq B$  the BCD difference is available at the F outputs in its true form. If  $A < B$ , the 10's complement of the correct answer appears at the F outputs with  $C_{in}/\overline{B_{in}}$  high or if  $C_{in}/\overline{B_{in}}$  is low the 9's complement results. As long as  $A < B$  an active low borrow is also generated.

The 82S82 BCD arithmetic unit is also useful for binary to BCD conversion. By summing  $B=0$  with binary inputs  $0 \leq A \leq 15$ , where A is the number being converted, a true BCD output results. A carry is generated to the next decade for  $A > 9$ .

The function table for the 82S82 summarizes the device operation. In those applications where only BCD addition is required, the Signetics 82S82 BCD adder should be considered.

### FUNCTION TABLE

FUNCTION	$\overline{ADD/SUB}$	A(A <sub>8</sub> ,A <sub>4</sub> ,A <sub>2</sub> ,A <sub>1</sub> )	B(B <sub>8</sub> ,B <sub>4</sub> ,B <sub>2</sub> ,B <sub>1</sub> )	C <sub>in</sub> / $\overline{B_{in}}$	F(F <sub>8</sub> ,F <sub>4</sub> ,F <sub>2</sub> ,F <sub>1</sub> )	C <sub>out</sub> / $\overline{B_{out}}$	COMPARE (A = B)
Add	0	BCD Augend	BCD Addend	1=Carry 0=No Carry	IF C <sub>in</sub> = 1 F = A + B + 1 IF C <sub>in</sub> = 0 F = A + B	F ≤ 9 C <sub>out</sub> / $\overline{B_{out}}$ =0 F > 9 C <sub>out</sub> / $\overline{B_{out}}$ =1	X
Subtract	1	BCD Minuend	BCD Subtrahend	0=Borrow 1=No Borrow	IF B <sub>in</sub> = 0 F = A - B - 1 IF B <sub>in</sub> = 1 F = A - B	A > B C <sub>out</sub> / $\overline{B_{out}}$ =1 A ≤ B C <sub>out</sub> / $\overline{B_{out}}$ =0 A < B C <sub>out</sub> / $\overline{B_{out}}$ =0 A ≥ B C <sub>out</sub> / $\overline{B_{out}}$ =1	X
Compare	1	BCD Word A	BCD Word B	1	A - B	A < B C <sub>out</sub> / $\overline{B_{out}}$ =0 A > B C <sub>out</sub> / $\overline{B_{out}}$ =1	If A=B Compare =1 If A≠B Compare =0
Binary to BCD Conversion	0	0 ≤ A ≤ 15	B = 0	X	BCD	A ≤ 9 C <sub>out</sub> = 0 A > 9 C <sub>out</sub> = 1	X

## D.C. ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS		NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS	OUTPUTS	
"1" Output Voltage	2.6	3.5		V	0.8V;2.0V	-1 mA	6, 8
"0" Output Voltage			0.5	V	0.8V;2.0V	16 mA	7, 8
"1" Output Leakage Current (A=B Output)			250	$\mu$ A	0.8V;2.0V	5.5V	8
"0" Input Current A <sub>N</sub> , B <sub>1</sub> , B <sub>8</sub> , C <sub>in</sub> / $\overline{B_{in}}$ B <sub>2</sub> , B <sub>4</sub> , Add/Sub			-400	$\mu$ A	0.5V		
			-800	$\mu$ A	0.5V		
"1" Input Current A <sub>N</sub> , B <sub>1</sub> , B <sub>8</sub> , C <sub>in</sub> / $\overline{B_{in}}$ B <sub>2</sub> , B <sub>4</sub> , Add/Sub			10	$\mu$ A	4.5V		
			20	$\mu$ A	4.5V		
Input Clamp Voltage			-1.2V	V	-18 mA		
Output Short Circuit Current	-20		-100	mA		OV	9,10
Power Consumption/ Supply Current		420/84	620/122	mW/mA			9

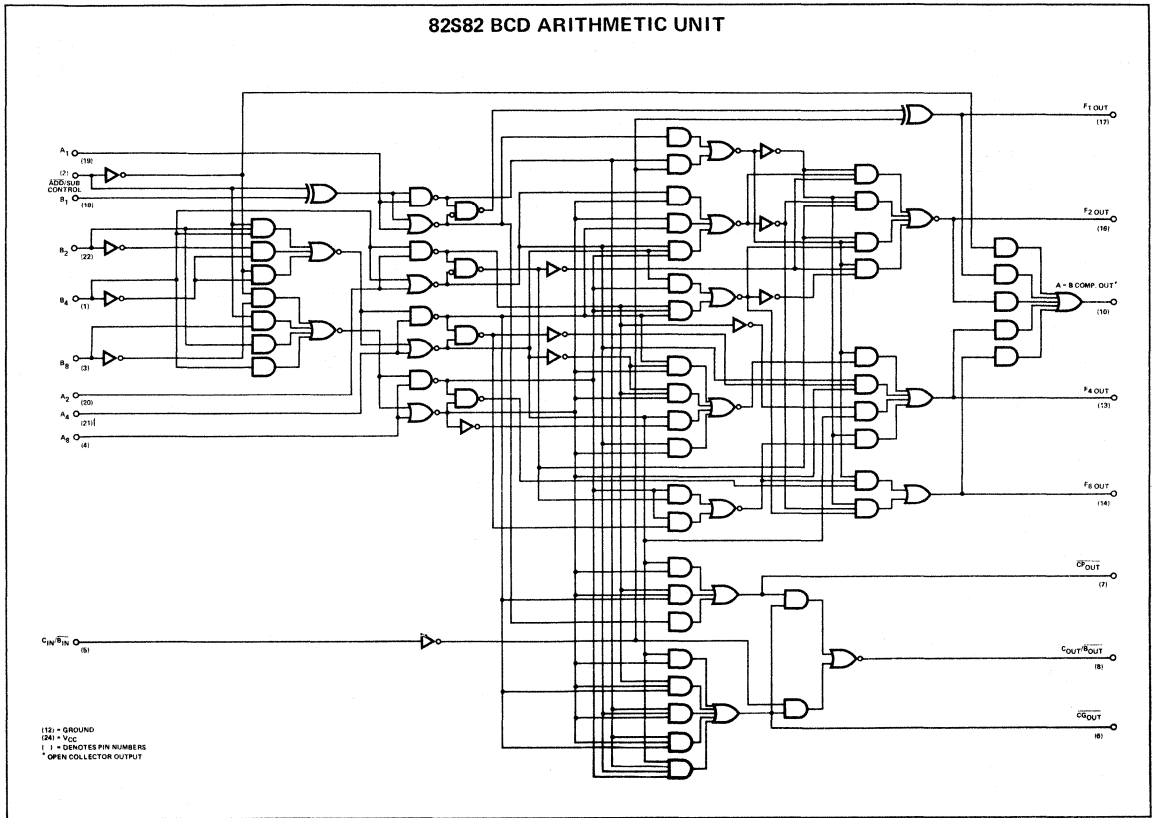
A.C. ELECTRICAL CHARACTERISTICS  $T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$ 

CHARACTERISTIC	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Turn On/Turn Off Delays Any A <sub>N</sub> , B <sub>N</sub> , C <sub>in</sub> / $\overline{B_{in}}$ to F <sub>N</sub>		22	35	ns	R <sub>L</sub> = 280 $\Omega$ C <sub>L</sub> = 15pF	8, 11
		22	35	ns		
Any A <sub>N</sub> to C <sub>out</sub> / $\overline{B_{out}}$ t <sub>on</sub>		32	40	ns		
		22	35	ns		
Any B <sub>N</sub> to C <sub>out</sub> / $\overline{B_{out}}$ t <sub>on</sub>		35	45	ns		
		26	35	ns		
C <sub>in</sub> / $\overline{B_{in}}$ to C <sub>out</sub> / $\overline{B_{out}}$ t <sub>on</sub>		17	25	ns		
		10	15	ns		
Add/Sub to F <sub>N</sub> t <sub>on</sub>		25	35	ns		
		25	35	ns		
A <sub>N</sub> , B <sub>N</sub> , to $\overline{C_{pout}}$ t <sub>on</sub>		19	25	ns		
		19	25	ns		
A <sub>N</sub> , B <sub>N</sub> to $\overline{C_{9out}}$ t <sub>on</sub>		19	25	ns		
		25	32	ns		
A <sub>N</sub> , B <sub>N</sub> to (A = B) t <sub>on</sub>		32	50	ns		
		40	50	ns		

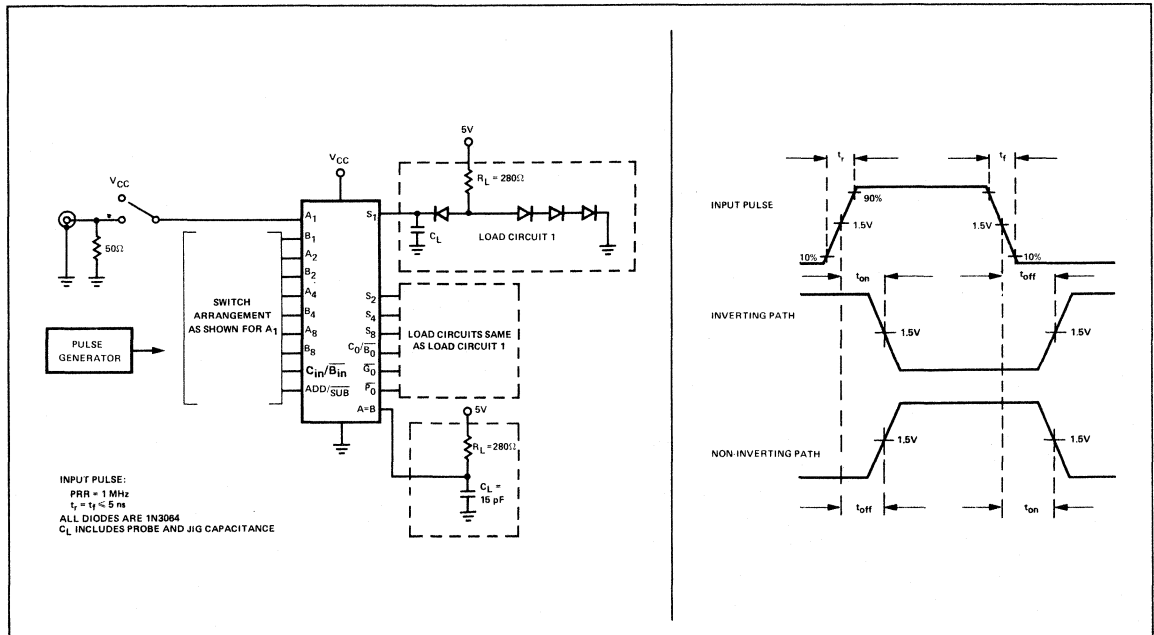
## NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are electrically left open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken in accordance with the Absolute Maximum Ratings.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to V<sub>CC</sub>.
- Input and output states are defined in accordance with the function table.
- V<sub>CC</sub> = 5.25V.
- Not more than one output should be shorted at a time.
- Refer to AC test figure.

LOGIC DIAGRAM



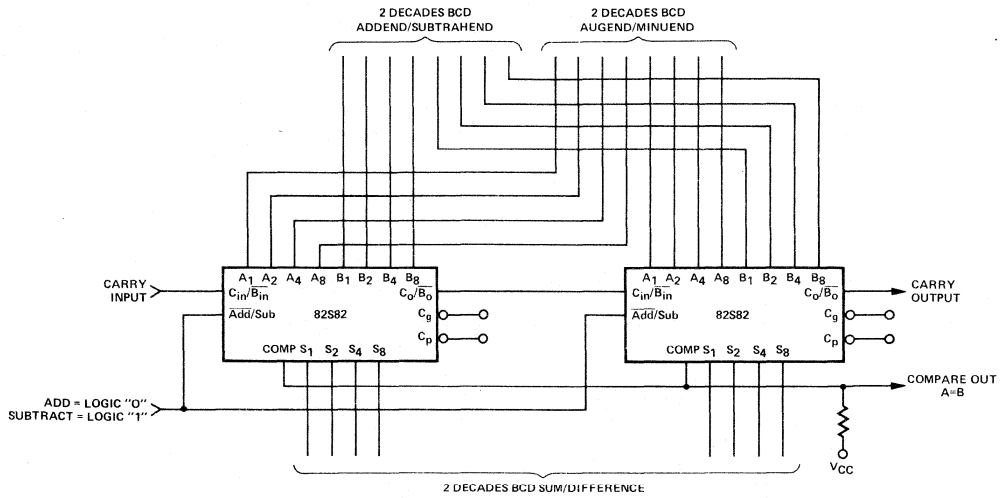
A.C. TEST FIGURE AND WAVEFORMS



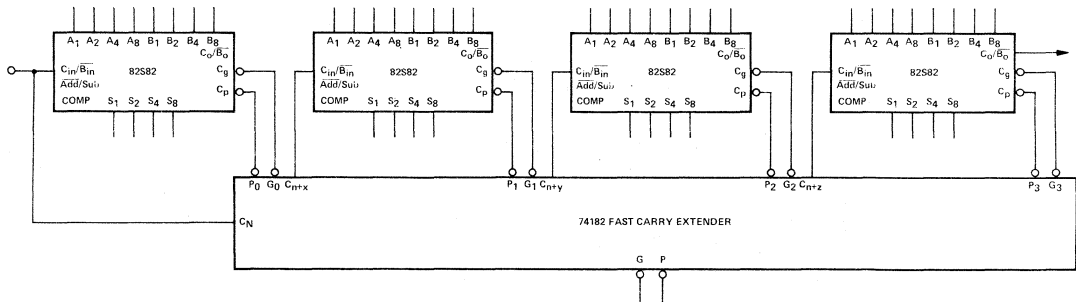


82S82 BCD ARITHMETIC UNIT APPLICATIONS

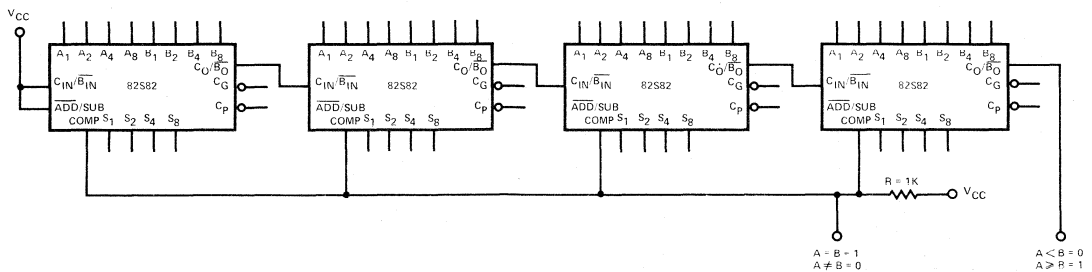
2 DECADE ADDER/SUBTRACTOR



FAST BCD ADDITION/SUBTRACTION USING FAST CARRY EXTENDER

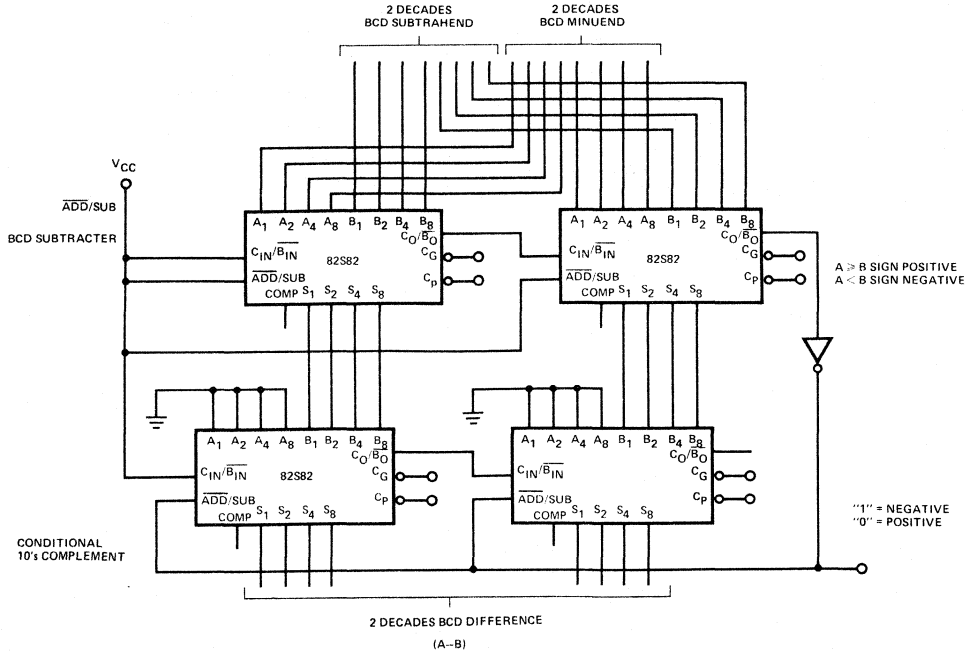


NUMBER COMPARISON OF BCD DECADES



82S82 BCD ARITHMETIC UNIT APPLICATIONS (Cont'd)

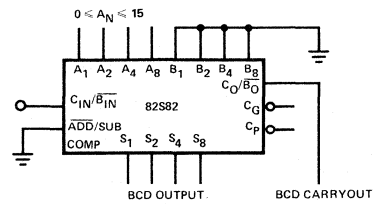
SIGN AND MAGNITUDE GENERATION FOR (A - B)



BINARY TO BCD CONVERSION

TRUTH TABLE FOR BINARY TO BCD CONVERSION  
( $10 \leq A_N \leq 15, B_N = 0$ )

Add/Sub	C <sub>in</sub> /B <sub>in</sub>	A <sub>8</sub>	A <sub>4</sub>	A <sub>2</sub>	A <sub>1</sub>	S <sub>8</sub>	S <sub>4</sub>	S <sub>2</sub>	S <sub>1</sub>	C <sub>out</sub> /B <sub>out</sub>
0	0	1	0	1	0	0	0	0	0	1
0	0	1	0	1	1	0	0	0	1	1
0	0	1	1	0	0	0	0	1	0	1
0	0	1	1	0	1	0	0	1	1	1
0	0	1	1	1	0	0	1	0	0	1
0	0	1	1	1	1	0	1	0	1	1
0	1	1	0	1	0	0	0	0	1	1
0	1	1	0	1	1	0	0	1	0	1
0	1	1	1	0	0	0	0	1	1	1
0	1	1	1	0	1	0	1	0	0	1
0	1	1	1	1	0	0	1	0	1	1
0	1	1	1	1	1	0	1	1	0	1



## DIGITAL 8000 SERIES SCHOTTKY TTL/MSI

### DESCRIPTION

The 82S83 4-bit binary coded (BCD) adder is a high speed Schottky MSI circuit that has been designed for easy systems usage. This unit produces the BCD sum of two decimal numbers presented in the 8-4-2-1 weighted BCD format. Carry-in and carry-out terms are provided for easy expansion to any number of decades. The 82S83 BCD adder has been designed such that input and output logic levels including the carry are in their true logic form.

Compared to cumbersome hardware implementations previously at the designer's disposal that consist of binary addition followed by decimal correction, the 82S83 BCD adder generates the BCD carry terms internally in the look-ahead mode and does BCD addition directly. For valid BCD numbers (0 through 9) at the A and B inputs the BCD sum is formed at the output. If addition  $(A+B+C_{IN})$  would yield a number greater than 9, a valid BCD number and a carry result.

Input codes above 9 are not defined except for binary to BCD conversion. Binary to BCD conversion is obtained by applying any 4-bit binary number to the  $A_N$  or  $B_N$  inputs while the remaining inputs are grounded. For input codes 0 through 9 a BCD number result at the output is usual. If binary inputs 10 through 15 are applied a carry term is generated and the carry output together with the sum out are the BCD equivalent of the binary input. Conversion of binary numbers greater than 16 can be achieved by cascading 82S83's

Subtraction can be done with the 82S83 by using 9's complement addition. Rather than implementing a 9's complement circuit with gates or ROM's, the 82S83 BCD arithmetic unit should be used. The 82S83 incorporates the 9's complement feature and performs BCD addition, BCD subtraction, and number comparison.

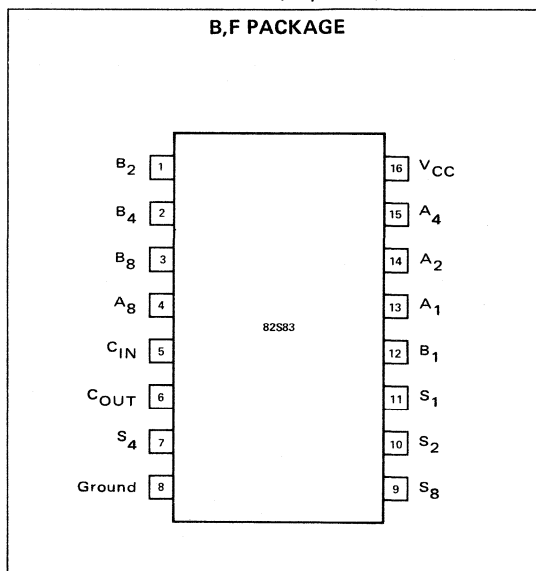
### 82S83 BCD ADDER PIN DESIGNATIONS

Pin Designation	Pin Nos.	Function
$A_8, A_4, A_2, A_1$	4, 15, 14, 13	BCD Inputs Word A Weighted (8-4-2-1)
$B_8, B_4, B_2, B_1$	3, 2, 1, 12	BCD Inputs Word B Weighted (8-4-2-1)
$S_8, S_4, S_2, S_1$	9, 7, 10, 11	BCD Sum Outputs Weighted (8-4-2-1)
$C_{in}$	5	Carry Input
$C_{out}$	6	Carry Output
VCC	16	Supply Voltage
GND	8	Ground

### FEATURES

- SCHOTTKY DESIGN FOR HIGH SPEED
- LOW CURRENT PNP INPUTS
- ADDS BCD NUMBERS
- CONVERTS BINARY TO BCD
- INTERNAL LOOK-AHEAD CARRY
- RIPPLE CARRY OUTPUT
- EASY ARRAY EXPANSION
- LOW POWER/CURRENT CONSUMPTION

### PIN CONFIGURATION (Top View)



### TRUTH TABLE

Decimal Equivalent	BCD CODE			
	8	4	2	1
0	0	0	0	0
1	0	0	0	1
2	0	0	1	0
3	0	0	1	1
4	0	1	0	0
5	0	1	0	1
6	0	1	1	0
7	0	1	1	1
8	1	0	0	0
9	1	0	0	1

D.C. ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature and Voltage

CHARACTERISTIC	LIMITS				TEST CONDITIONS		NOTES
	MIN.	TYP.	MAX.	UNITS	INPUTS	OUTPUTS	
"1" Output Voltage	2.6	3.5		V	0.8V; 2.0V	-1 mA	6, 8
"0" Output Voltage			0.5	V	0.8V; 2.0V	16 mA	7, 8
"0" Input Current			-400	$\mu$ A	0.5V		
"1" Input Current			10	$\mu$ A	4.5V		
Input Clamp Voltage			-1.2	V	-18 mA		
Output Short Circuit Current	-20		-100	mA		OV	9, 10
Power Consumption/ Supply Current		399/ 76	598/ 114	mW/ mA			9

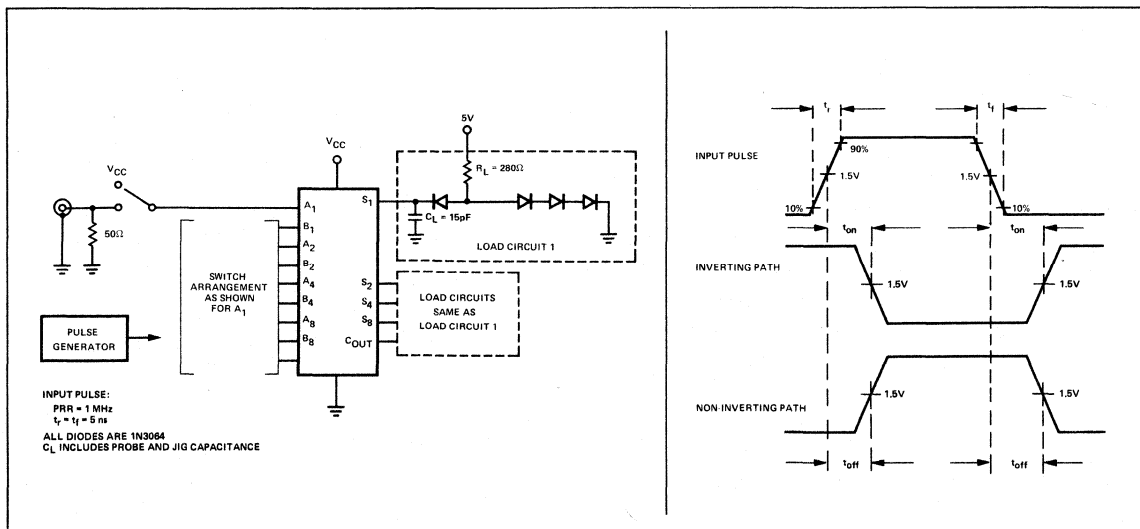
A.C. ELECTRICAL CHARACTERISTICS  $T_A = 25^\circ\text{C}$  and  $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Turn-On/Turn-Off Delays ( $t_{on}, t_{off}$ )					$R_L = 280\Omega$ $C_L = 15\text{pF}$	8, 11
Any $A_N, B_N, C_{in}$ to $S_N$	$t_{on}$	20	35	ns		
	$t_{off}$	20	35	ns		
Any $A_N, B_N,$ to $C_{out}$	$t_{on}$	33	40	ns		
	$t_{off}$	17	25	ns		
$C_{in}$ to $C_{out}$	$t_{on}$	17	25	ns		
	$t_{off}$	10	15	ns		

NOTES

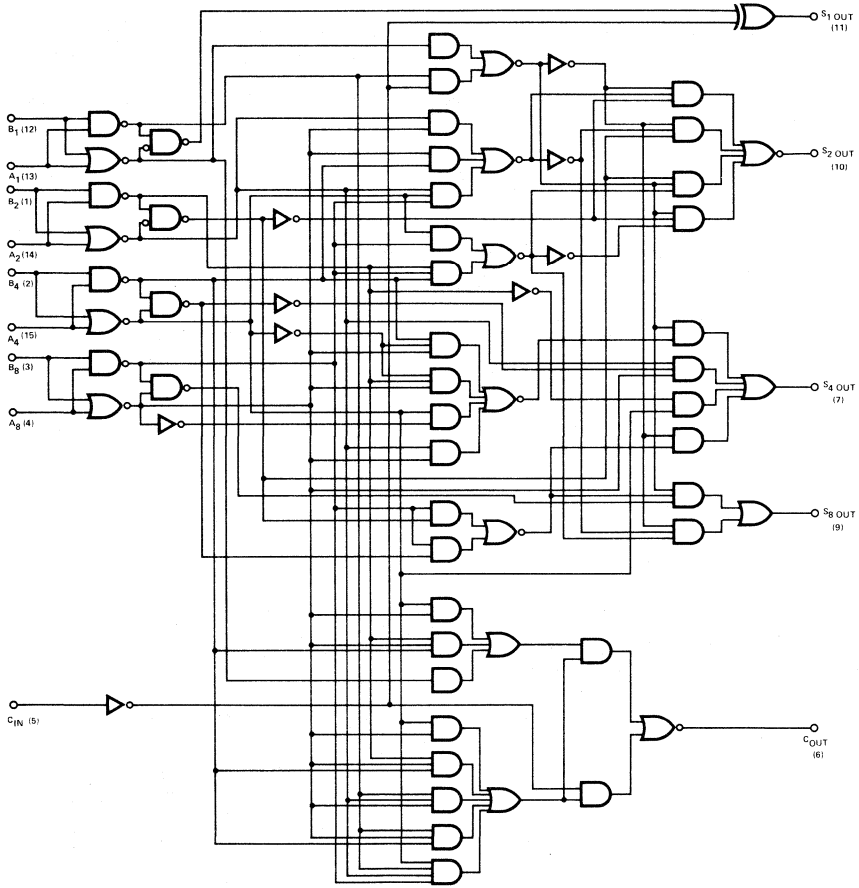
1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are electrically left open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current is defined as into the terminal referenced.
4. Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken in accordance with the Absolute Maximum Ratings.
6. Output source current is supplied through a resistor to ground.
7. Output sink current is supplied through a resistor to  $V_{CC}$ .
8. Output states are defined in accordance with valid BCD numbers resulting from  $A+B+C_{IN}=\text{Sum}$ .  $C_{OUT}=1$  when  $A+B+C_{IN}>9$ , otherwise  $C_{OUT}=0$
9.  $V_{CC} = 5.25\text{V}$
10. Not more than one output should be shorted at a time.
11. Refer to AC test figures.

A.C. TEST FIGURE AND WAVEFORMS



LOGIC DIAGRAM

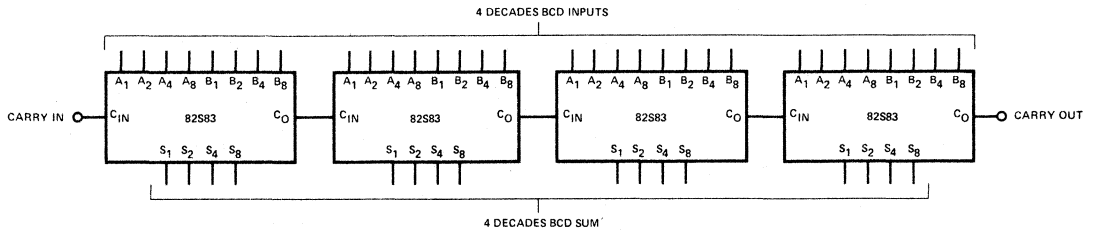
82S83 BCD ADDER



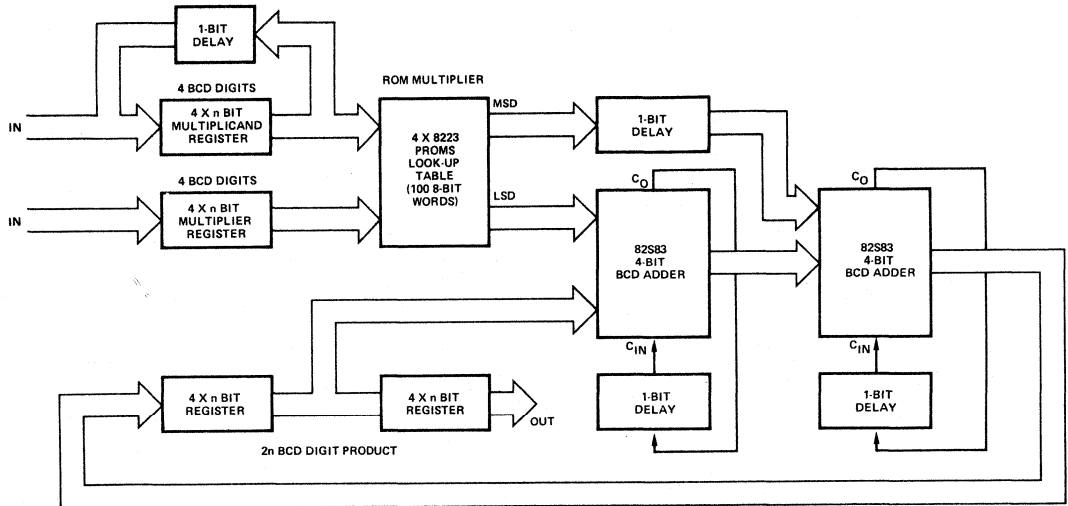
V<sub>CC</sub> = (16), GND = (8),  
 ( ) = Denotes Pin Numbers

82S83 BCD ADDER APPLICATIONS

PARALLEL ADDITION OF FOUR DECADES



BIT PARALLEL-WORD SERIAL BCD MULTIPLIER

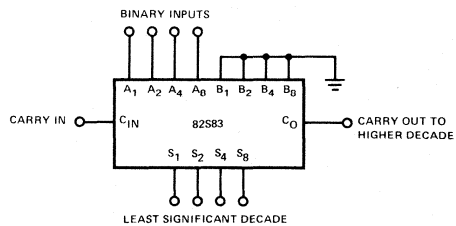


82S83 BCD ADDER APPLICATIONS (Cont'd)

BINARY TO BCD CONVERSION USING  $A_i$  INPUTS

PARTIAL TRUTH TABLE FOR  $A_i > 9, B_i = 0$

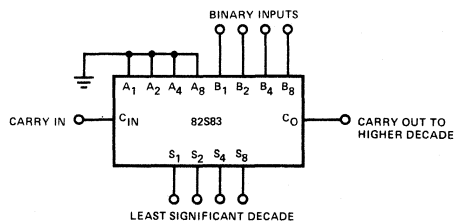
$C_{IN}$	$A_1$	$A_2$	$A_4$	$A_8$	$B_1$	$B_2$	$B_4$	$B_8$	$S_1$	$S_2$	$S_4$	$S_8$	$CO$
0	0	1	0	1	0	0	0	0	0	0	0	0	1
0	1	1	0	1	0	0	0	0	1	0	0	0	1
0	0	0	1	1	0	0	0	0	0	1	0	0	1
0	1	0	1	1	0	0	0	0	1	1	0	0	1
0	0	1	1	1	0	0	0	0	0	0	1	0	1
0	1	1	1	1	0	0	0	0	1	0	1	0	1
1	0	1	0	1	0	0	0	0	1	0	0	0	1
1	1	1	0	1	0	0	0	0	0	1	0	0	1
1	0	0	1	1	0	0	0	0	1	1	0	0	1
1	1	0	1	1	0	0	0	0	0	0	1	0	1
1	0	1	1	1	0	0	0	0	1	0	1	0	1
1	1	1	1	1	0	0	0	0	0	1	1	0	1



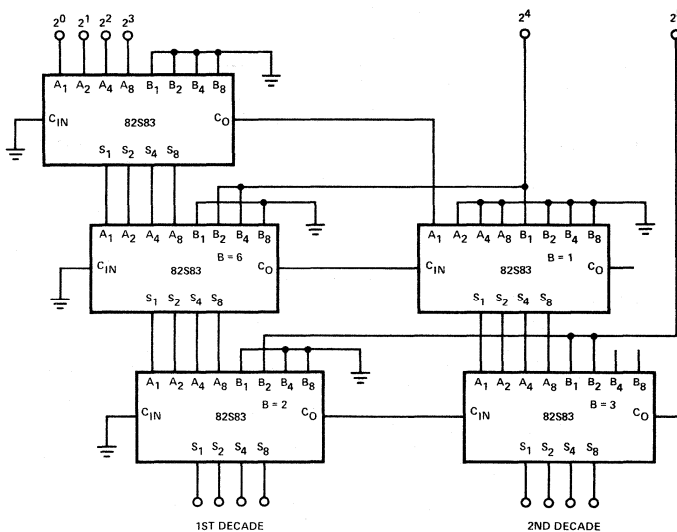
BINARY TO BCD CONVERSION USING  $B_i$  INPUTS

PARTIAL TRUTH TABLE FOR  $B_i > 9, A_i = 0$

$C_{IN}$	$A_1$	$A_2$	$A_4$	$A_8$	$B_1$	$B_2$	$B_4$	$B_8$	$S_1$	$S_2$	$S_4$	$S_8$	$CO$
0	0	0	0	0	0	1	0	1	0	0	0	0	1
0	0	0	0	0	1	1	0	1	1	0	0	0	1
0	0	0	0	0	0	0	1	1	0	1	0	0	1
0	0	0	0	0	1	0	1	1	1	1	0	0	1
0	0	0	0	0	0	1	1	1	0	0	1	0	1
0	0	0	0	0	1	1	1	1	1	0	1	0	1
1	0	0	0	0	0	1	0	1	1	0	0	0	1
1	0	0	0	0	1	1	0	1	0	1	0	0	1
1	0	0	0	0	0	0	1	1	1	1	0	0	1
1	0	0	0	0	1	0	1	1	0	0	1	0	1
1	0	0	0	0	0	1	1	1	1	0	1	0	1
1	0	0	0	0	1	1	1	1	0	1	1	0	1



BINARY TO BCD CONVERSION FOR 2 DECADES



#### DESCRIPTION

The 82S90 Decade Counter and 82S91 Binary Counter are pin-compatible ultra high speed versions of the popular 8280/8290 Decade and 8281/8291 Binary Counters. They are multifunctional MSI building blocks capable of being used in computer applications, frequency synthesis, digital integration and wherever ultra high speed is essential.

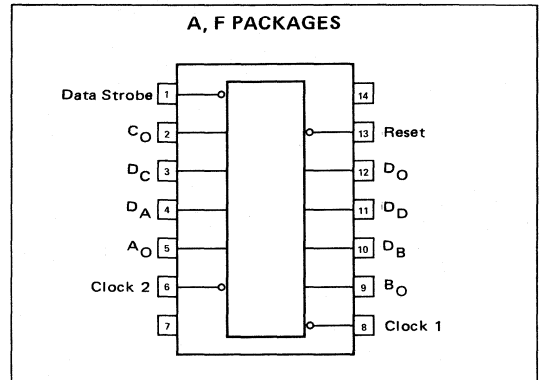
#### FEATURES

- 100 MHz TYPICAL COUNT FREQUENCY
- LOW CURRENT PNP INPUTS
- $\div 2, 4, 5, 8, 10$  AND 16 OR VARIABLE MODULUS
- STROBED PARALLEL ENTRY
- PIN REPLACEABLE FOR THE 8290/8291, 74196/74197

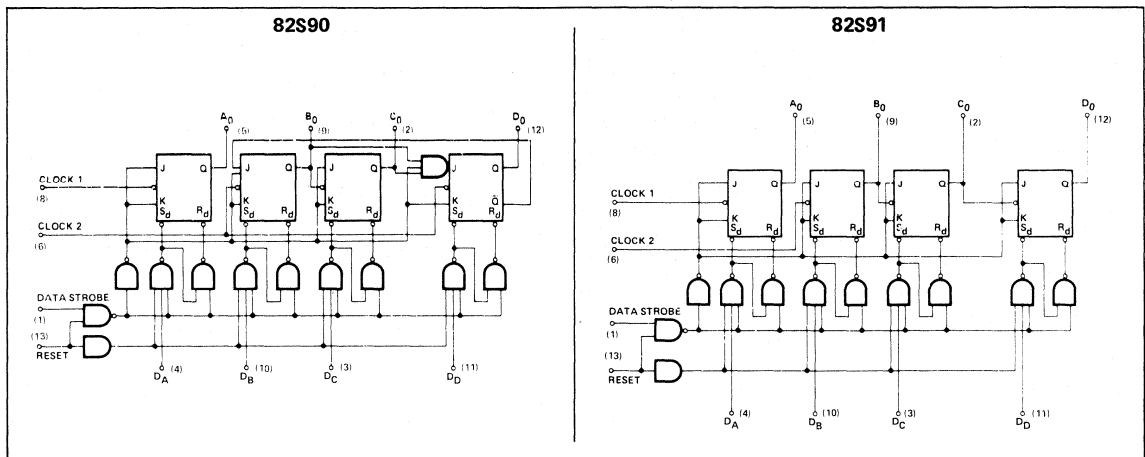
#### PIN DESIGNATIONS

CP <sub>1</sub>	Clock input to counter first stage (active low going edge)
CP <sub>2</sub>	Clock input to counter last three stages (active low going edge)
DS	Data Strobe Input for enabling data entry (active low)
RS	Reset Input for resetting all stages and outputs to zero (active low)
D <sub>A</sub> , D <sub>B</sub> , D <sub>C</sub> , D <sub>D</sub>	Data Inputs
A <sub>O</sub> , B <sub>O</sub> , C <sub>O</sub> , D <sub>O</sub>	Data Outputs

#### PIN CONFIGURATION (Top View)



#### LOGIC DIAGRAMS





FUNCTIONAL DESCRIPTION

1. 82S90 Decade Counter

The 82S90 can be used in three basic count modes as follows:

- a. BCD Counter. The CP2 input must be connected to the A<sub>0</sub> output and CP1 receives the count input. The count sequence obtained is BCD in accordance with the truth table.
- b. Bi-Quinary Counter. If a symmetrical output is required for divide by 10 operation, the D<sub>0</sub> output must be connected to the CP1 input and the count input applied to CP2. A symmetrical square wave is then obtained at A<sub>0</sub> of one-tenth the input frequency present at CP2 in accordance with the truth table.
- c. Separate Divide by Two and Five Counters. Because the inherent structure of the counter is that of two separate divide by two and divide by five sections, no other connections are required for this mode of operation. An input presented to CP1 will appear at A<sub>0</sub> output at half the input frequency. An input presented to CP2 will appear at outputs B<sub>0</sub>, C<sub>0</sub> and D<sub>0</sub> as a binary divide by five count (i.e., from 0 = 000 to 4 = 100). Operation of the D<sub>S</sub> and R<sub>S</sub> inputs remain common to all four flip flops as with any other count mode.

TRUTH TABLES

Decade (BCD)				
Input	A <sub>0</sub>	B <sub>0</sub>	C <sub>0</sub>	D <sub>0</sub>
0	0	0	0	0
1	1	0	0	0
2	0	1	0	0
3	1	1	0	0
4	0	0	1	0
5	1	0	1	0
6	0	1	1	0
7	1	1	1	0
8	0	0	0	1
9	1	0	0	1

Bi-Quinary (5-2)				
Input	A <sub>0</sub>	B <sub>0</sub>	C <sub>0</sub>	D <sub>0</sub>
0	0	0	0	0
1	0	1	0	0
2	0	0	1	0
3	0	1	1	0
4	0	0	0	1
5	1	0	0	0
6	1	1	0	0
7	1	0	1	0
8	1	1	1	0
9	1	0	0	1

2. 82S91 Binary Counter

The 82S90 can be used in two basic count modes as follows:

- a. Binary Counter—For this mode of operation A<sub>0</sub> output must be connected to CP2 input and the count input connected to CP1. Subdivisions of the count input frequency then appear at A<sub>0</sub> = ÷2, B<sub>0</sub> = ÷4, C<sub>0</sub> = ÷8, D<sub>0</sub> = ÷16 as shown in the truth table.
- b. Separate Divide by Two and Divide by Eight Counters—In similar manner to the 82S90 the 82S91 inherent structure allows separate use of the first and last three stages. In the first stage the input count frequency presented to CP2 appears at outputs B<sub>0</sub> = ÷2, C<sub>0</sub> = ÷4 and D<sub>0</sub> = ÷8 simultaneously. Operation of the D<sub>S</sub> and R<sub>S</sub> inputs remains common to all stages.

TRUTH TABLE

Binary				
Input	A <sub>0</sub>	B <sub>0</sub>	C <sub>0</sub>	D <sub>0</sub>
0	0	0	0	0
1	1	0	0	0
2	0	1	0	0
3	1	1	0	0
4	0	0	1	0
5	1	0	1	0
6	0	1	1	0
7	1	1	1	0
8	0	0	0	1
9	1	0	0	1
10	0	1	0	1
11	1	1	0	1
12	0	0	1	1
13	1	0	1	1
14	0	1	1	1
15	1	1	1	1

3. Operation of the D<sub>S</sub> Data Strobe and R<sub>S</sub> Reset Inputs:

- a. Data Strobe D<sub>S</sub> Input When D<sub>S</sub> = 0 the four stages of the 82S90/91 can be used as four separate latches with the outputs A<sub>0</sub> - D<sub>0</sub> following the data presented to the inputs D<sub>A</sub> - D<sub>D</sub> regardless of clock inputs.

With D<sub>S</sub> = 1 the four stages remain unchanged until the next clock inputs, which activate counting in accordance with the various modes described previously. The Reset R<sub>S</sub> inputs when low overrides D<sub>S</sub> as described below.

- b. Reset R<sub>S</sub> Input With R<sub>S</sub> = 0 the clock inputs CP1/CP2 and D<sub>S</sub> input are overridden, all stages of the 82S90/91 are cleared and zeros appear at the counter outputs A<sub>0</sub> - D<sub>0</sub>. When R<sub>S</sub> = 1, operation is controlled by D<sub>S</sub> or CP1/CP2 clock inputs as described.

# SIGNETICS ULTRA HIGH SPEED PRESETTABLE DECADE BINARY COUNTER ■ 82S90/82S91

## D.C. ELECTRICAL CHARACTERISTICS Over Recommended Operating Temperature And Voltage

CHARACTERISTICS	LIMITS				TEST CONDITIONS						NOTES	
	MIN	TYP	MAX	UNITS	DATA STROBE	DATA INPUTS	RESET	CLOCK 1	CLOCK 2	OUTPUTS		
"1" Output Voltage	2.6	3.5		V	0.8V	2.0V	2.0V				-1mA	6, 8
"0" Output Voltage			0.5	V	0.8V	0.8V	0.8V				20mA	6, 9
"0" Input Current												
Data Strobe			-400	μA			5.25V					
Data Inputs			-400	μA								
Reset			-400	μA	5.25V							
Clock 1			-6.0	mA	5.25V							
Clock 2 (8290)			-6.0	mA	5.25V							
Clock 2 (8291)			-3.0	mA	5.25V							
"1" Input Current												
Data Strobe			10	μA	4.5V		0.0V					
Data Inputs			10	μA		4.5V						
Reset			10	μA	0.0V		4.5V					
Clock 1			100	μA	0.0V			4.5V				
Clock 2 (8290)			100	μA	0.0V				4.5V			
Clock 2 (8291)			50	μA	0.0V				4.5V			
Output Short Circuit Current	-40		-100	mA	0.0V	4.5V					0.0V	10, 11
Power Consumption/ Supply Current		308 62	461 88	mW/ mA			0.0V	0.0V	0.0V			11

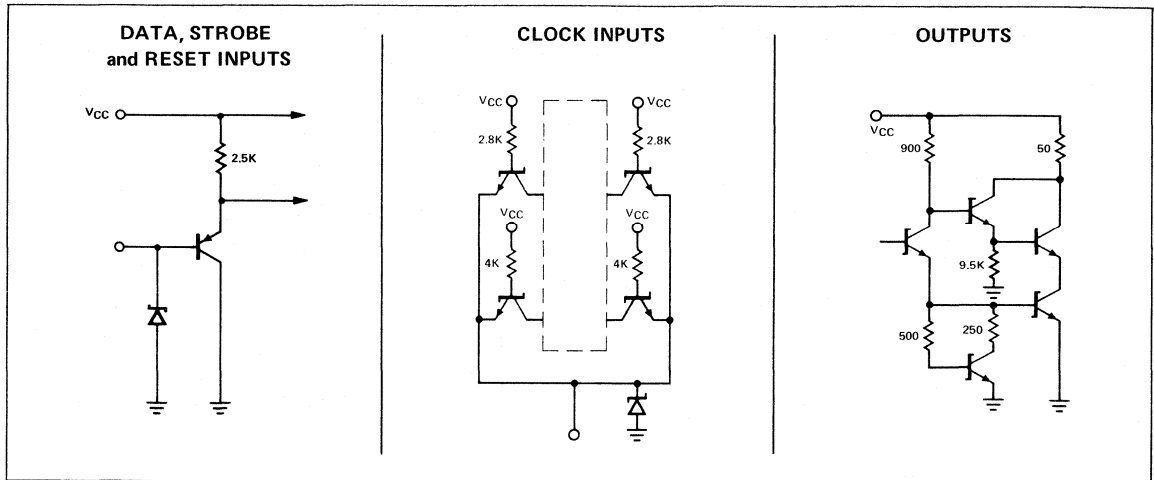
## A.C. ELECTRICAL CHARACTERISTICS $T_A = 25^\circ\text{C}$ and $V_{CC} = 5.0\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN	TYP	MAX	UNITS		
Strobe Pulse Width		5	10	ns	Per A.C. Test Figures $R_L = 280\Omega$ $C_L = 15\text{pF}$	9
Reset Pulse Width		7	15	ns		
Strobe/Reset Release Time		10	15	ns		
Clock Mode $t_{ON}$ Delay						
Bit A		9	12	ns		
Bits B, C, D		10	13	ns		
Clock Mode $t_{OFF}$ Delay						
Bit A		5	8	ns		
Bits B, C, D		6	10	ns		
Strobed Data $t_{ON}$ Delay						
(All Bits)		15	22	ns		
Strobed Data $t_{OFF}$ Delay						
(All Bits)		13	20	ns		
Toggle Rate	85	100		MHz		

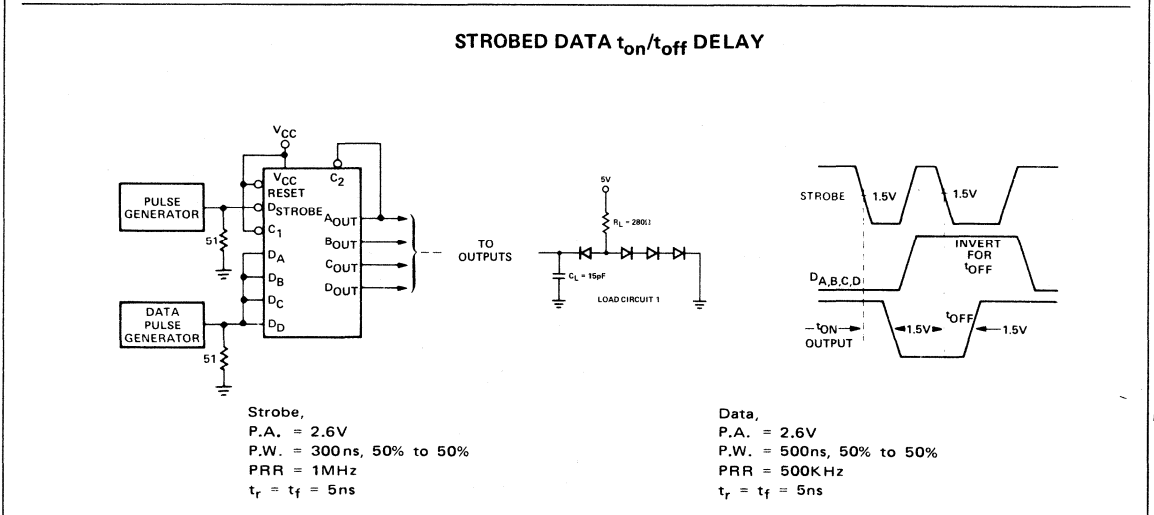
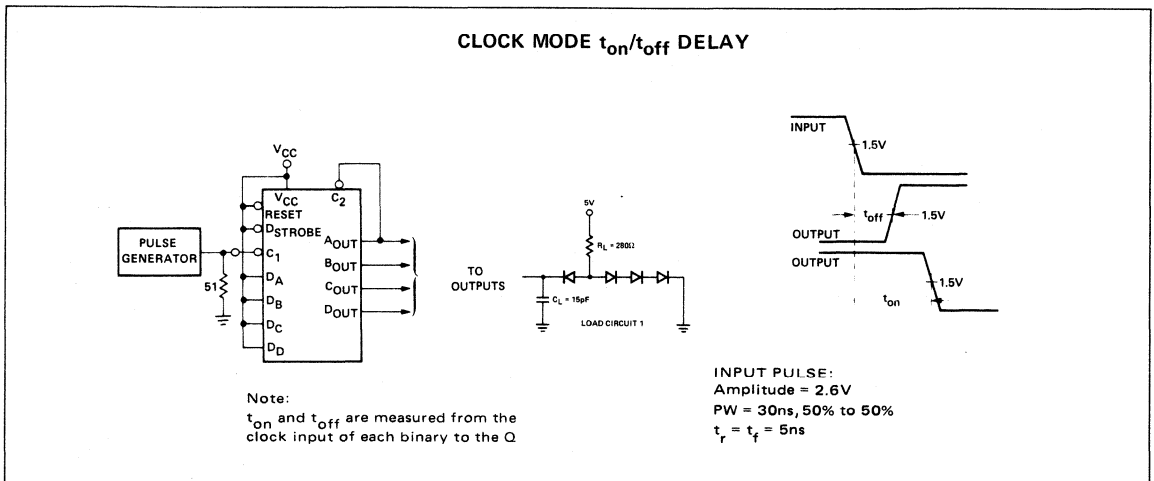
### NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive NAND Logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings.
- Measurements apply to each output and the associated data input independently.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figures and Waveforms.
- Not more than one output should be shorted at a time.
- $V_{CC} = 5.25\text{V}$ .

INPUT AND OUTPUT STRUCTURES



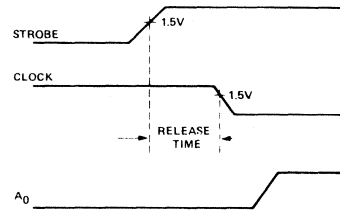
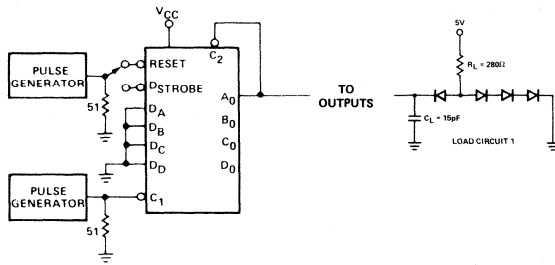
A.C. TEST FIGURES AND WAVEFORMS





A.C. TEST FIGURES AND WAVEFORMS (Cont'd)

STROBE/RESET RELEASE TIME



CLOCK, STROBE/RESET:  
 Amplitude = 2.6V  
 PRR = 1MHz, 50% duty cycle  
 $t_r = t_f = 5ns$  max.

NOTES

1. All resistor values are in ohms.
2. All capacitance values are in picofarads and include jig and probe capacitance.
3. All diodes are 1N3064.



**signetics**

BIPOLAR  
MEMORY PRODUCT  
SPECIFICATIONS







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## Bipolar Memory Functional Index

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<b>RAM</b>		
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<b>New Product</b>		
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## ABSOLUTE MAXIMUM RATINGS\*

CHARACTERISTICS	SYMBOL	RATING	UNIT
<b>TTL MEMORIES</b>			
Storage Temperature	T <sub>STG</sub>	-60 to +150	°C
Output and Supply Voltages	V <sub>OUT</sub> , V <sub>CC</sub>	-0.5 to +6.0	V
Input Voltages	V <sub>IN</sub>	-0.5 to +6.0	V
Output Currents	I <sub>OUT</sub>	100	mA
Input Currents	I <sub>IN</sub>	-30 to +30	mA
<b>ECL MEMORIES</b>			
Power Supply Voltage (V <sub>CC</sub> = 0)	V <sub>EE</sub>	-8	Vdc
Input Voltage (V <sub>CC</sub> = 0)	V <sub>IN</sub>	0 to V <sub>EE</sub>	Vdc
Output Source Current	I <sub>o</sub>		
Continuous		50	mAdc
Surge		100	mAdc
Storage Temperature Range	T <sub>stg</sub>	-54 to +175	°C
Operating Junction Temperature	T <sub>J</sub>	125	°C
Operating Temperature Range	T <sub>A</sub>	-30 to +85	°C
Power Supply Regulation Required	—	±10%	—

\*These ratings do not imply that the device will function or meet the specified parameters at the levels indicated. They do, however, indicate those levels at which permanent damage and/or parameter degradation could occur. Exposure to these levels over extended periods of time could affect reliability and should, therefore, be avoided.

### DIGITAL 8000 SERIES TTL/MEMORY

#### DESCRIPTION

The 8205 and 8204 are high performance bipolar ROM's incorporating the storage output or memory data register into the chip. Data is addressed by applying address information to the address lines. After valid data appears at the output of the memory array, (typically 35ns after the address is applied) and if the circuit is enabled, the strobe pulse will enter data into the 8 bit output latch register. A D-type latch (L) is used to enable the tri-state output drivers. If the circuit enable signals are valid, the strobe will set the latch. This turns on the output stage. The latch will remain set and keep the output enabled until the chip is disabled and the next strobe pulse occurs. If the strobe line is held high, the ROM will function in a conventional mode. The output will be controlled solely by the chip enable and the output latches will be bypassed.

Refer to back of Bipolar Memory section for ASCII (ADDRESS) to EBCDIC (DATA) and EBCDIC (ADDRESS) to ASCII (DATA) and ORDERING BLANKS.

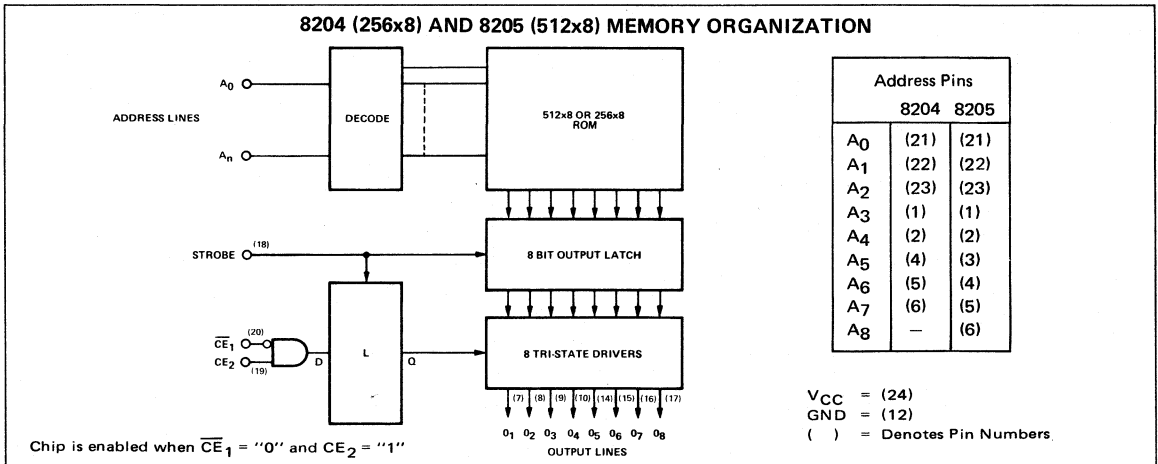
#### FEATURES

- BUFFERED ADDRESS LINES
- ON THE CHIP DECODING
- ON THE CHIP STORAGE LATCHES
- TRI-STATE OUTPUT
- PROTECTED INPUTS

#### APPLICATIONS

MICROPROGRAMMING  
HARDWARE ALGORITHMS  
CHARACTER GENERATION  
CONTROL STORE

#### BLOCK DIAGRAM



#### ELECTRICAL CHARACTERISTICS $0^\circ C \leq T_A \leq 75^\circ C$ ; $4.75V \leq V_{CC} \leq 5.25V$

CHARACTERISTICS	LIMITS			UNIT	TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.			
Input "0" Current			-400	$\mu A$	$V_{in} = 0.45V$	
Input "1" Current			25	$\mu A$	$V_{in} = 5.5V$	
Input (0) Threshold Voltage			85	V		
Input (1) Threshold Voltage	2			V		
Input Clamp Voltage	-1.2V			V	$I_{in} = -18mA$	
Output (0) Current		0.25	0.5	V	$I_{out} = 9.6mA$	
Output (1) Current	2.7	3.3		V	$I_{out} = -2.0mA$	
Output (1) Short Circuit Current	-20	-35	-70	mA	$V_{out} = 0V, V_{CC} = 5.0V$	
Input Capacitance		5		pF	$V_{IH} = 2.0V, V_{CC} = 5.0V$	
Output Capacitance		8		pF	$V_{out} = 2.0V, V_{CC} = 5.0V$	
Power Supply Current		135	170	mA	$V_{CC} = 5.0V$	
Output (1) off Leakage Current (Chip Disabled)			40	$\mu A$	$V_{out} = 5.5V$	
Output (0) off Leakage Current (Chip Disabled)			-40	$\mu A$	$V_{out} = 0.45V$	

SWITCHING CHARACTERISTICS  $0 \leq T_A \leq 75^\circ\text{C}$ ,  $4.75 \leq V_{CC} \leq 5.25\text{V}$

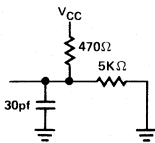
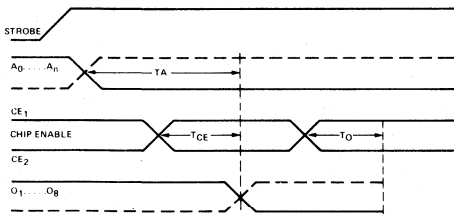
CHARACTERISTICS	LIMITS			UNIT	TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.			
Address Access Time $T_A$		35	75	ns	Read Mode I or Read Mode II	6
Address Hold Time $T_{ADS}$	0	-10		ns	Read Mode 2 Only	6
Chip Enable Access Time $T_{CE}$		20	50	ns	Read Mode I or Read Mode II	6
Chip Enable Hold Time $T_{CDS}$	15	5		ns	Read Mode II Only	6
Output Disable Time $T_O$		20	50	ns	Read Mode I or Read Mode II	6
Strobe Pulse Width $T_{SW}$	35	20		ns	Read Mode II Only	6
Strobe Set-Up Time $T_S$		30	75	ns	Read Mode II Only	6
Output Disable Time $T_R$		18	35	ns	Read Mode II Only	6

NOTES

1. Positive current is defined as into the terminal referenced.
2. No more than one output should be grounded at the same time and strobe should be disabled. Strobe is in "1" state.
3. Manufacturer reserves the right to make design and process changes and improvements.
4. Applied voltages must not exceed 6.0V. Input currents must not exceed  $\pm 30$  mA. Output currents must not exceed  $\pm 100$  mA. Storage temperature must be between  $-60^\circ\text{C}$  to  $+150^\circ\text{C}$ .
5. Chip disabled.
6. Rise and fall times for tests must be less than 5ns. Input amplitudes are 2.8V and all measurements are made at 1.5V.

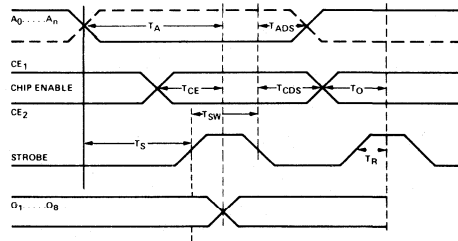
MEMORY TIMING

READ MODE I (OUTPUT LATCHES NOT USED)

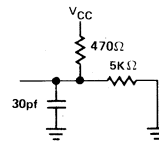


If the strobe is high, the device functions in a manner identical to conventional bipolar ROM's. The timing diagram shows valid data will appear  $T_A$  nanoseconds after the address has changed and  $T_{CE}$  nanoseconds after the output circuit is enabled.  $T_O$  is the time required to disable the output and switch it to an 'off' or high impedance state after it has been enabled.

READ MODE II (OUTPUT LATCHES USED)



NOTE: T Cycle Time =  $T_A + T_{ADS} + T_{SW} + T_{CDS}$



In Read Mode II, data from any selected address will be held on the output when strobe is lowered. Only when strobe is raised will new location data be transferred and chip enable conditions be stored. The new data will appear on the outputs if the chip enable conditions enable the outputs.

### DIGITAL 8000 SERIES TTL/MEMORY

#### DESCRIPTION

The 8220 CAM Element is a high speed monolithic array, incorporating the necessary addressing logic and eight identical memory cells organized as four words, each being two bits long. In reference to data-in/data-stored, the 8220 can be conditioned to perform the following functions: associate, write-in only, and read-out only.

When addressed into the "ASSOCIATE" mode, this element offers the novel capability of data association, where each cell ( $M_{nj}$ ) will respond with a "Match" or "Mismatch" answer ( $Y_n$ ) to each bit presented to the data inputs ( $I_j$ ), depending on presence or absence of an alike bit stored within the cell.

Write-in can be simultaneously done to all bits, or one bit at a time. Read-out of stored information is performed on one word at a time. Cell-selection for read and write is performed by proper addressing of  $Y_n$  and  $A_n$  lines.

The element's output structures ( $Y_n$  and  $D_j$ ) are of the "bare collector" variety and can be mutually connected, thus allowing direct expansion when multiple packages are employed. Expansion of the CAM may be implemented in

both directions, i.e., in the word length and in the number of words.

The CAM circuit structure is the familiar TTL type (DCL Family) and fully compatible with TTL and DTL input/output structures.

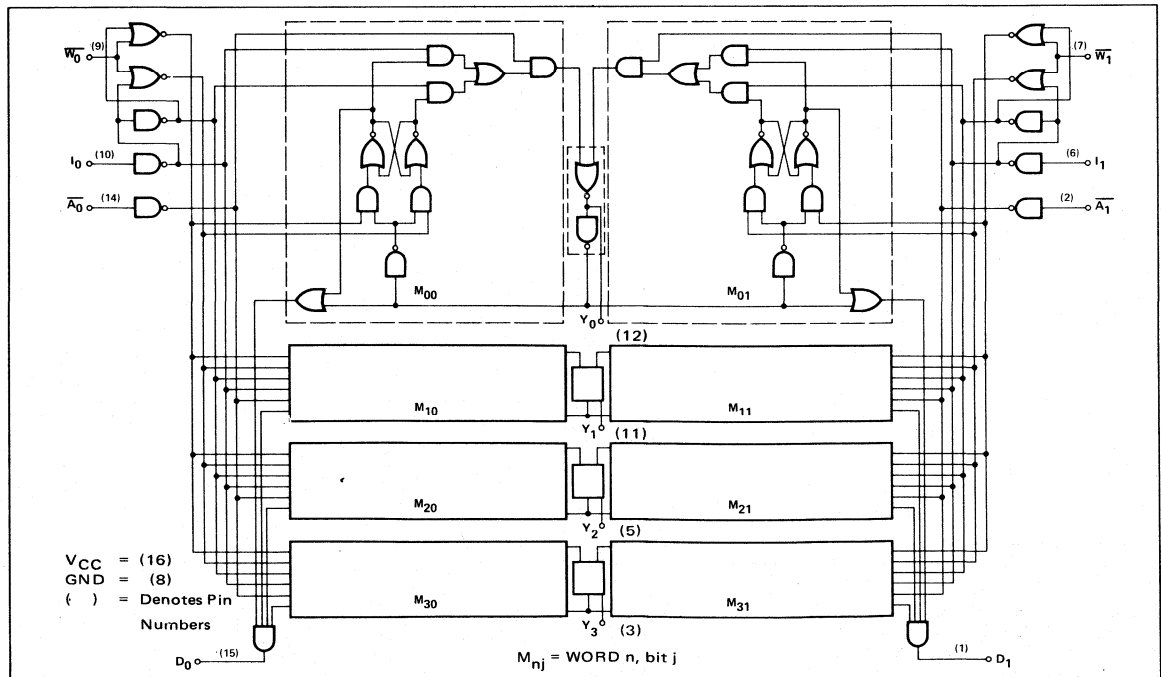
#### FEATURES

- WRITE ENABLE CONTROL LINES
- ASSOCIATE CONTROL LINES
- ADDRESS SELECT CONTROL LINES
- ASSOCIATES IN 20nsec TYP.
- 16 PIN PACKAGE (1/3 SIZE OF 24 PIN PACKAGE)
- OPEN COLLECTOR OUTPUTS
- DIODE PROTECTED INPUTS

#### APPLICATIONS

- DATA-TO-MEMORY COMPARISON
- PATTERN RECOGNITION
- HIGH SPEED INFORMATION RETRIEVAL
- CACHE MEMORY
- AUTO CORRELATION
- VIRTUAL MEMORY
- LEARNING MEMORY

#### LOGIC DIAGRAM



ELECTRICAL CHARACTERISTICS  $0^{\circ}\text{C} \leq T_A \leq 75^{\circ}\text{C}; 4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				$\bar{W}_j$	$\bar{A}_j$	$I_j$	$Y_i$	$Y_k$	$D_j$	NOTES
	MIN.	TYP.	MAX.	UNITS							
"0" Output Voltage											
Yn			0.4	V	2.0V	0.8V	2.0V	30mA			8, 9
			0.6	V	2.0V	0.8V	2.0V	60mA			
Dj			0.4	V	2.0V	2.0V			0.8V	20mA	8, 9
			0.6	V	2.0V	2.0V			0.8V	40mA	
"1" Output Leakage Current											
Yn			125	$\mu\text{A}$		2.0V					10
Dj			100	$\mu\text{A}$				0V	0V		10
"1" Input Current											
Ij and $\bar{A}_j$			40	$\mu\text{A}$		4.5V	4.5V				
$\bar{W}_j$			80	$\mu\text{A}$	4.5V						
"0" Input Current											
Ij, Yn and $\bar{A}_j$	-0.1		-1.2	mA		0.4V	0.4V	0.4V			
$\bar{W}_j$			-2.4	mA							
Power Consumption		85/ 425	118/ 590	mA/mW	V <sub>CC</sub> = 5.0 Volts						

SWITCHING CHARACTERISTICS  $0 \leq T_A \leq 75^{\circ}\text{C}, 4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				NOTES
	MIN.	TYP.	MAX.	UNITS	
Delay Time					
Associate (Aj to Yn)		20	35	ns	See Notes 8 & 11
Associate (Ij to Yn)		45	65	ns	See Notes 8 & 11
Read-Out (Yn to Dj)		30	45	ns	See Notes 8 & 11
Write-In to Read-Out (Wj to Dj)		45	65	ns	See Notes 8 & 11
Write Pulse Width	35	20		ns	See Notes 8 & 11
Ij Set-Up Time (I <sub>SO</sub> )	10			ns	See Notes 8 & 11
Ij Hold Time (I <sub>HO</sub> )	10			ns	See Notes 8 & 11

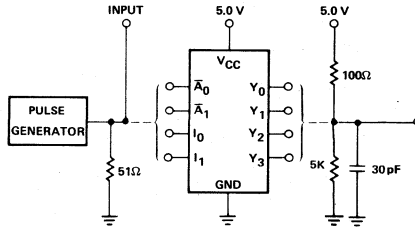
- NOTES
- All voltage and capacitance measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
  - All measurements are taken with ground pin tied to zero volts.
  - Positive current is defined as into the terminal referenced.
  - Positive NAND logic definition: "UP" Level = "1", "DOWN" Level = "0".
  - Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
  - Measurements apply to each gate element independently.
  - Manufacturer reserves the right to make design and process changes and improvements.
  - Prior to this test write in a "0" in all or desired Memory cells as follows:  $W_j = I_j = 0V, A_j = V_{CC}$ .
  - Output sink current is supplied through a resistor to V<sub>CC</sub>.
  - Connect an external 1K ohm + 1% resistor from V<sub>CC</sub> to the output terminal for this test.
  - See AC test Figures on the following pages.

MODE OF OPERATION

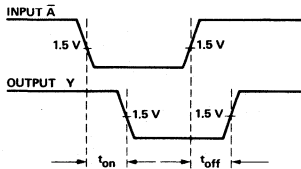
FUNCTION	$\overline{W}_0 \overline{W}_1 \overline{A}_0 \overline{A}_1 I_0 I_1$	REMARKS (Ref. Definitions & Glossary)	FUNCTION	$\overline{W}_0 \overline{W}_1 \overline{A}_0 \overline{A}_1 I_0 I_1$	REMARKS (Ref. Definitions & Glossary)															
HOLD	1 1 1 1 x x	NO OPERATION	HOLD	1 1 1 1 x x	NO OPERATION															
ASSOCIATE	1 1 1 0 x x	<table border="1"> <tr> <th>Question</th> <th>Answer</th> <th>Output State</th> </tr> <tr> <td><math>I_1 = M_{i1}</math></td> <td>YES</td> <td><math>Y_i = 1, Y_k = 0</math></td> </tr> <tr> <td></td> <td>NO</td> <td><math>Y_i = Y_k = 0</math></td> </tr> </table>	Question	Answer	Output State	$I_1 = M_{i1}$	YES	$Y_i = 1, Y_k = 0$		NO	$Y_i = Y_k = 0$	WRITE-IN	1 0 1 1 x x	<table border="1"> <tr> <th colspan="2">Forced</th> </tr> <tr> <th><math>Y_i</math></th> <th><math>Y_k</math></th> </tr> <tr> <td>1</td> <td>0</td> </tr> </table> WRITE $I_1$ into $M_{i1}$	Forced		$Y_i$	$Y_k$	1	0
	Question	Answer	Output State																	
	$I_1 = M_{i1}$	YES	$Y_i = 1, Y_k = 0$																	
	NO	$Y_i = Y_k = 0$																		
Forced																				
$Y_i$	$Y_k$																			
1	0																			
1 1 0 1 x x	<table border="1"> <tr> <th>Question</th> <th>Answer</th> <th>Output State</th> </tr> <tr> <td><math>I_0 = M_{i0}</math></td> <td>YES</td> <td><math>Y_i = 1, Y_k = 0</math></td> </tr> <tr> <td></td> <td>NO</td> <td><math>Y_i = Y_k = 0</math></td> </tr> </table>	Question	Answer	Output State	$I_0 = M_{i0}$	YES	$Y_i = 1, Y_k = 0$		NO	$Y_i = Y_k = 0$	0 1 1 1 x x	<table border="1"> <tr> <th colspan="2">Forced</th> </tr> <tr> <th><math>Y_i</math></th> <th><math>Y_k</math></th> </tr> <tr> <td>1</td> <td>0</td> </tr> </table> WRITE $I_0$ into $M_{i0}$	Forced		$Y_i$	$Y_k$	1	0		
Question	Answer	Output State																		
$I_0 = M_{i0}$	YES	$Y_i = 1, Y_k = 0$																		
	NO	$Y_i = Y_k = 0$																		
Forced																				
$Y_i$	$Y_k$																			
1	0																			
1 1 0 0 x x	<table border="1"> <tr> <th>Question</th> <th>Answer</th> <th>Output State</th> </tr> <tr> <td><math>I_1 = M_{i1}</math> and <math>I_0 = M_{i0}</math></td> <td>YES</td> <td><math>Y_i = 1, Y_k = 0</math></td> </tr> <tr> <td></td> <td>NO</td> <td><math>Y_i = Y_k = 0</math></td> </tr> </table>	Question	Answer	Output State	$I_1 = M_{i1}$ and $I_0 = M_{i0}$	YES	$Y_i = 1, Y_k = 0$		NO	$Y_i = Y_k = 0$	0 0 1 1 x x	<table border="1"> <tr> <th colspan="2">Forced</th> </tr> <tr> <th><math>Y_i</math></th> <th><math>Y_k</math></th> </tr> <tr> <td>1</td> <td>0</td> </tr> </table> WRITE $I_1$ and $I_0$ into $M_{i1}$ and $M_{i0}$	Forced		$Y_i$	$Y_k$	1	0		
Question	Answer	Output State																		
$I_1 = M_{i1}$ and $I_0 = M_{i0}$	YES	$Y_i = 1, Y_k = 0$																		
	NO	$Y_i = Y_k = 0$																		
Forced																				
$Y_i$	$Y_k$																			
1	0																			
			READ-OUT	1 1 1 1 x x	$D_0 = 1$ - IF $M_{i0} = 1$ $D_0 = 0$ - IF $M_{i0} = 0$															
				1 1 1 1 x x	$D_1 = 1$ - IF $M_{i1} = 1$ $D_1 = 0$ - IF $M_{i1} = 0$															
				1 1 1 1 x x	$D_0 = D_1 = 1$															

AC TEST FIGURES AND WAVEFORMS

ASSOCIATE DELAY AND INPUT DELAY



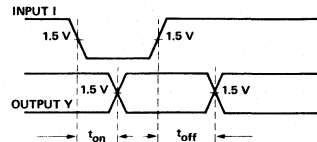
ASSOCIATE DELAY



NOTES:

1. When checking  $\overline{A}_0$  let  $\overline{A}_1 = "1"$  and when checking  $\overline{A}_1$  let  $\overline{A}_0 = "1"$ .
2.  $\overline{W}_0 = \overline{W}_1 = "1"$ .

INPUT DELAY



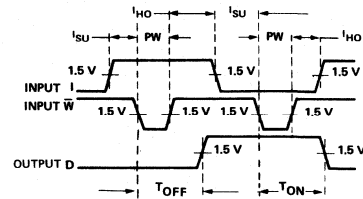
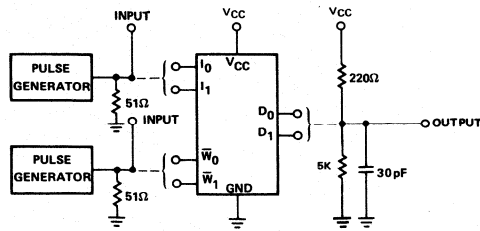
NOTES:

1. When checking  $I_1$ ,  $\overline{A}_1 = "0"$  and  $\overline{A}_0 = "1"$  and when checking  $I_0$ ,  $\overline{A}_0 = "0"$  and  $\overline{A}_1 = "1"$
2.  $\overline{W}_0 = \overline{W}_1 = "1"$ .



## AC TEST FIGURES AND WAVEFORMS (Cont'd)

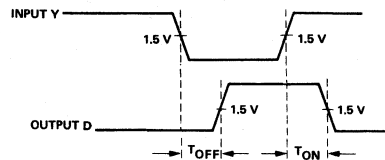
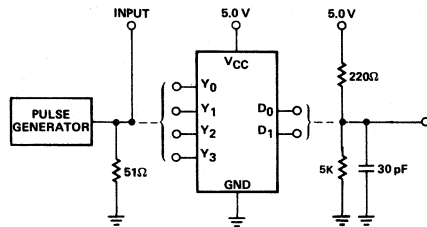
## WRITE DELAY



## NOTES:

1.  $A_0 = A_1 = "1"$ .
2. Let all non-selected Y's = "0".
3. W's pulse width is 40ns @50% points.

## READ DELAY



## NOTES:

1. A tested bit must store a "0".
2.  $W_0 = W_1 = "1"$ .
3.  $A_0 = A_1 = "1"$ .
4. All non-tested Y's = "0".

## GENERAL NOTES FOR AC TESTING:

1. Use 5k Probes for all AC tests TEK 169 or equivalent.
2. The Pulse Generator signal should consist of the following  
Frequency: 10 MHz  $\pm$  5 MHz  
Amplitude: 0V to 3V  
Rise & Fall Times: 5 ns  $\pm$  2ns
3.  $i$  = bit number ( $i = 0, 1$ ).  $j$  = word number ( $j = 0, 1, 2, 3$ ).

## INPUT/OUTPUT DEFINITIONS

- $I_j$  — Data Inputs  
Data entering these terminals are either compared with stored information at the cell(s) in the "associate" mode or stored in the cell(s) in the "write-in" mode.
- $\bar{A}_j$  — Associate Controls  
A logical "0" at this pin enables Data-Cell association to result into a defined logical level at the  $Y_n$  lines (e.g.  $Y_n = "1"$  = Match,  $Y_n = "0"$  = Mismatch). A logical "1" at this pin, forces all  $Y_n$  to a "1".
- $\bar{W}_j$  — Write Enable  
A logical "0" at this control pin opens the gates of the selected word, allowing data-in to be stored. A logical "1" locks the gates such that data-in can no longer disturb the cell(s).
- $Y_n$  — "Associate" Output and Address Selection Control  
During "Associate" mode these "bare collector" lines provide output results of match or mismatch between input and stored

data (logical "1" = Match, logical "0" = Mismatch).

In the read and write modes these terminals act as input controls and word-select lines Y lines ( $Y_1$ ) associated with words desired to accept writing of data or read-out are to be kept in the logical "1" state and the remaining Y lines ( $Y_k$ ) to be forced to a logical "0" state. (Note that  $A = 1$  forces all  $Y_n = 1$ ).

 $D_j$  — Data Output

These are "bare collector" output lines indicating the state of one or more selected cells. Cell-Selection is accomplished as defined under " $Y_n$ " above.

## GLOSSARY OF TERMS — SUBSCRIPTS

- A.  $n$  = Word number = 0, 1, 2 and 3  
 $j$  = Bit number = 0 or 1  
 $i$  = Input/Output number(s) associated with cell(s) upon which a "Write-in", "Read-out" or other function is being performed.  
 $k$  = Input/Output number(s) other than "i" above.  
 $M$  = Designation of Memory Cell (word) = eight identical cells in each package.
- B. Examples  
1.  $I_j$  for bit "1" equals  $I_1$ .  
2.  $M_{nj} = M_{10}$  = word "1" bit "0".  
3.  $Y_i = 0, Y_k = 1$ : for  $i$  = words 1 and 3; then  $k$  = words 0 and 2:  $Y_{1,3} = 0$  and  $Y_{0,2} = 1$ .



### DIGITAL 8000 SERIES TTL/MEMORY

#### DESCRIPTION

The 8223 is a TTL 256-Bit Read Only Memory organized as 32 words with 8 bits per word. The words are selected by five binary address lines; full word decoding is incorporated on the chip. A chip enable input is provided for additional decoding flexibility, which causes all eight outputs to go to the high state when the chip enable input is high.

This device is fully TTL or DTL compatible. The outputs are uncommitted collectors, which permits wired AND operation with the outputs of other TTL or DTL devices. These outputs are capable of sinking twelve standard DCL loads.

Propagation delay time is 50ns maximum. Power dissipation is 310 milliwatts with 400 milliwatts maximum. The 8223 may be programmed to any desired pattern by the user. (See fusing procedure.) This feature is ideal for prototype hardware and systems requiring propriety codes.

A Truth Table/Order Blank is included on page 4-43 for ordering custom patterns.

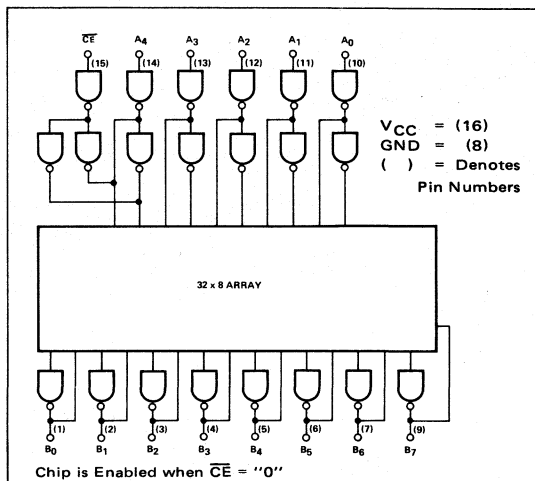
#### FEATURES

- BUFFERED ADDRESS LINES
- ON THE CHIP DECODING
- CHIP ENABLE CONTROL LINE
- OPEN COLLECTOR OUTPUTS
- DIODE PROTECTED INPUTS
- NO SEPARATE FUSING PINS
- BOARD LEVEL PROGRAMMABLE

#### APPLICATIONS

- PROTOTYPING
- VOLUME PRODUCTION
- MICROPROGRAMMING
- HARDWIRED ALGORITHMS
- CONTROL STORE

#### LOGIC DIAGRAM



#### ELECTRICAL CHARACTERISTICS S8223 $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ N8223 $0^{\circ}\text{C} \leq T_A \leq 75^{\circ}\text{C}$ ; $4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				"0" $A_n$	"1" $A_n$	$\overline{\text{CHIP}} \text{ ENABLE}$	OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS					
"1" Output Leakage Current (N8223-)			100	$\mu\text{A}$			2.0V	5.5V	13
(S8223-)			250	$\mu\text{A}$				2.7V	
"0" Output Voltage (N8223-)			0.4	V	0.8V	2.0V	0.8V	9.6mA	6,10
(S8223-)			0.5	V	0.8V	2.0V	0.8V	16mA	6,10
"1" Input Current									
$A_n$ , Address			40	$\mu\text{A}$		4.5V			
$\overline{\text{Chip Enable}}$ Input			80	$\mu\text{A}$			4.5V		
"0" Input Current									
$A_n$ , $\overline{\text{Chip Enable}}$	-0.1		-1.6	mA	0.4V		0.4V		
Power Consumption		62/310	77/400	mW/mA		4.5V	4.5V		14

**SIGNETICS 256-BIT FIELD PROGRAMMABLE ROM ■ 8223**

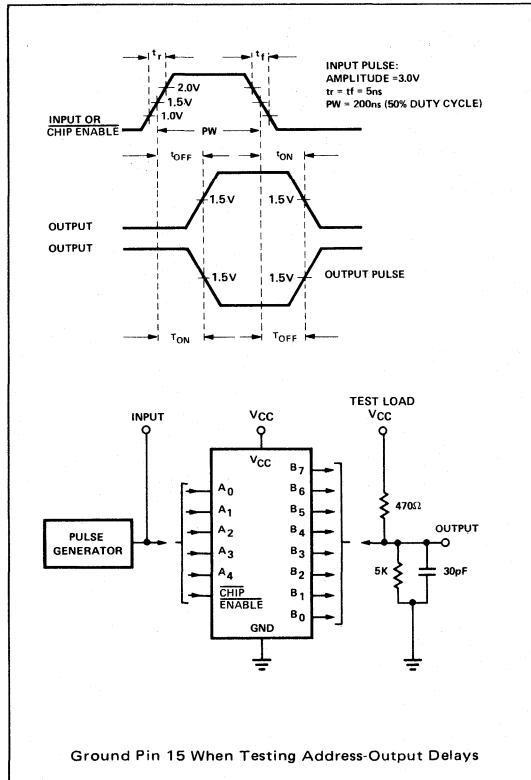
**SWITCHING CHARACTERISTICS** S8223  $-55^{\circ}\text{C} \leq T_A \leq 125^{\circ}\text{C}$ , N8223  $0 \leq T_A \leq 75^{\circ}\text{C}$ ,  $4.75 \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
Access Time ( $t_{ON}$ , $t_{OFF}$ )					
Address		35	50	ns	$T_A = 25^{\circ}\text{C}$ Only Full Temp
S8223			65	ns	
N8223			60	ns	Full Temp
Chip Select		35	50	ns	$T_A = 25^{\circ}\text{C}$ Only Full Temp
S8223			60	ns	
N8223			55	ns	Full Temp

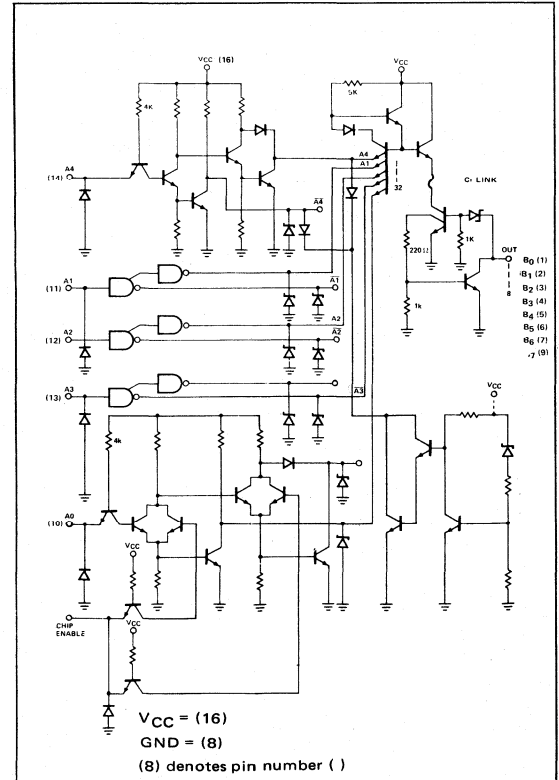
**NOTES**

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current is defined as into the terminal referenced.
4. Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
6. Output sink current is supplied through a resistor to  $V_{CC}$ .
7. One DC fan-out is defined as 0.8mA.
8. One AC fan-out is defined as 50pF.
9. Manufacturer reserves the right to make design and process changes and improvements
10. By DC tests per the truth table, all inputs have guaranteed thresholds of 0.8V for logical "0" and 2.0V for logical "1".
11. This test guarantees operation free of input latch-up over the specified operating power supply voltage range.
12. For detailed test conditions, see AC testing.
13. Connect an external 1k resistor from  $V_{CC}$  to the output terminal for this test.
14.  $V_{CC} = 5.25\text{V}$ .

**AC TEST FIGURE AND WAVEFORMS**



**SCHEMATIC DIAGRAM**



**8223 PROGRAMMING PROCEDURE**

The 8223 Standard part is shipped with all outputs at logical "0". To write a logical "1" proceed as follows:

**Simple Programming Procedure using "bench" Equipment**  
(See below)

1. Start with pin 8 grounded and V<sub>CC</sub> removed from pin 16.
2. Remove any load from the outputs.
3. Ground the Chip Enable.
4. Address the desired location by applying ground (i.e., 0.4V maximum) for a "0", and +5.0V (i.e., +2.8V minimum) for a "1" at the address input lines.
5. Apply +12.5V ±0.5V to the output to be programmed through a 390 ohm ±10% resistor. (Program one output at a time.)
6. After a short delay apply +12.5V to V<sub>CC</sub> (pin 16) and remove as quickly as possible (rise time of 50µsec or less). The V<sub>CC</sub> overshoot should be limited to 1.0V maximum. If necessary, a clamping circuit should be used.

NOTE: Normal practice in test fixture layout should be followed. Lead lengths, particularly to the power supply, should be as short as possible. A capacitor of 10 microfarads minimum, connected from the +12.5V to ground, should be located close to the unit being programmed.

7. Verify that the bit has programmed by applying 5 volts to V<sub>CC</sub> and 5 volts through a 1k resistor to the output.
8. Proceed to the next output and repeat, or change address and repeat.
9. Continue until the entire bit pattern is programmed into your custom 8223.

10. If during verification a bit had been found not to have programmed, return to that bit and repeat the programming procedure once.

**Fast Programming Procedure**

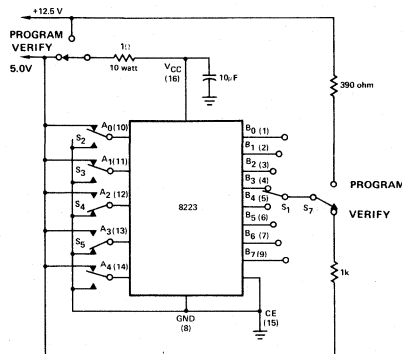
1. Remove V<sub>CC</sub> (open or ground pin 16).
2. Remove any load from the output.
3. Ground CE (pin 15)
4. Address the word to be programmed by applying 5 volts for a "1" and ground for a "0" to the address lines.
5. Apply +12.5V ±0.5V to the output to be programmed through a 390 ohm ±10% resistor. (Program one output at a time.)
6. After a minimum delay of 100µsec, apply +12.5V to V<sub>CC</sub> (pin 16) for 1.0mS. The V<sub>CC</sub> rise time must be 50µsec or less. Limit the V<sub>CC</sub> overshoot to 1.0 volts max.
7. Reduce V<sub>CC</sub> to ground (<0.5V) and remove the load from the output.
8. Repeat steps 5 and 6 for other outputs of the same word, or repeat 4 through 6 for a different word until the entire bit pattern is programmed.

After programming the 8223, the unit should be checked to insure the code is correct.

**BOARD LEVEL PROGRAMMING PROCEDURE FOR THE 8223**

The chip select controls which 8223 is being programmed when several PROMs are collector OR'd. To program in this manner, the only change required is to reduce the 390 ohm resistor to  $\frac{200 \text{ ohm}}{N}$  where N is the number of outputs tied together ( $2 \leq N \leq 12$ ).

**MANUAL PROGRAMMER DIAGRAM**



**NOTES**

1. The 10µF capacitor across pin 16 to ground is required to eliminate noise from V<sub>CC</sub>.
2. During programming switch S<sub>7</sub> must be in the verify position long enough for the 10µF capacitor to discharge to 5.0 volts.

### DIGITAL 8000 SERIES TTL/MEMORY

#### DESCRIPTION

The 8225 is a TTL 64-bit Read-Write Random Access Memory organized as 16-words of 4 bits each. The 8225 is ideally suited for application in scratch pads and high-speed buffer memories.

Words are selected through a 4-input binary decoder when the chip enable input ( $\overline{CE}$ ) is at logic "0". Data is written into the memory when Read Enable (RE) is at logic "0" and read from the memory when RE is at logic "1".

The outputs of the 8225 are logical "1" during write operation, therefore, inputs and outputs can be commoned in busses to reduce the number of I/O leads. Output collectors are uncommitted.

#### FEATURES

- CHIP ENABLE LINE FOR EXPANSION
- OPEN COLLECTOR OUTPUTS FOR EXPANSION
- ON THE CHIP DECODING
- ALL OUTPUTS "1" DURING WRITING
- DIODE PROTECTED INPUTS

#### APPLICATIONS

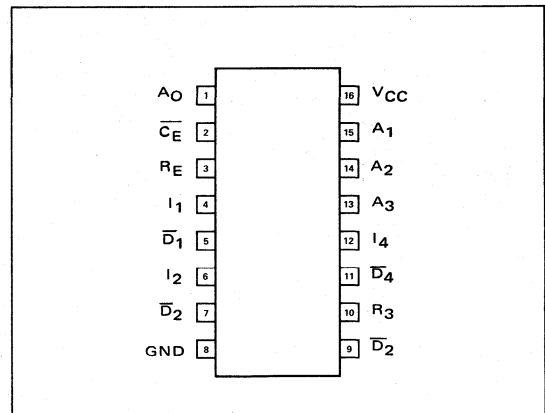
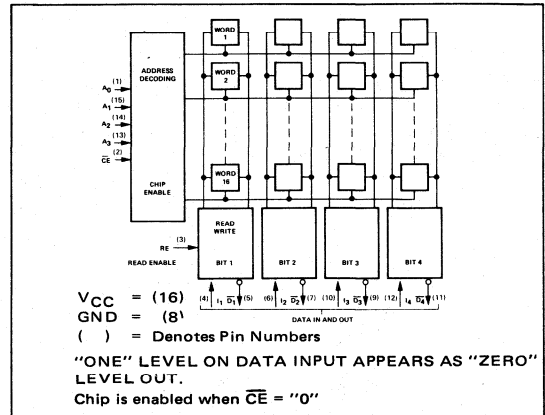
- SCRATCH PAD MEMORY
- BUFFER MEMORY
- PUSH DOWN STACKS (First in-first out)
- CONTROL STORE

#### TRUTH TABLE

RE	CE (Chip Enable)	MODE	OUTPUTS
0	0	Write	"1"
1	0	Read	Information
X	1	Chip Disable	"1"

X = Either State

#### BLOCK DIAGRAM



#### ELECTRICAL CHARACTERISTICS $0^\circ\text{C} \leq T_A \leq 75^\circ\text{C}$ ; $4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				CHIP ENABLE	INPUTS		DATA INPUTS	OUTPUTS	NOTES
	MIN.	TYP.	MAX.	UNITS		WRITE	ADDRESS			
"0" Output Voltage			.4	V	.8V	Pulse			16mA	6,8,0,
"1" Output Leakage Current			100	$\mu\text{A}$	.8V	Pulse		.8V	5.25V	8,9
"0" Input Current	-1		-1.6	mA	.4V	.4V	.4V	.4V		11
"1" Input Current										
Chip Enable			80	$\mu\text{A}$	4.5V					
Write, Address, Data			40	$\mu\text{A}$	4.5V	4.5V	4.5V	4.5V		11
Input Clamp Voltage	-1.5			V	-18mA	-18mA	-18mA	-18mA		11
Power Consumption		80	110/	mA/	0V	5V	0V	0V		10,5
		400	550	mW						

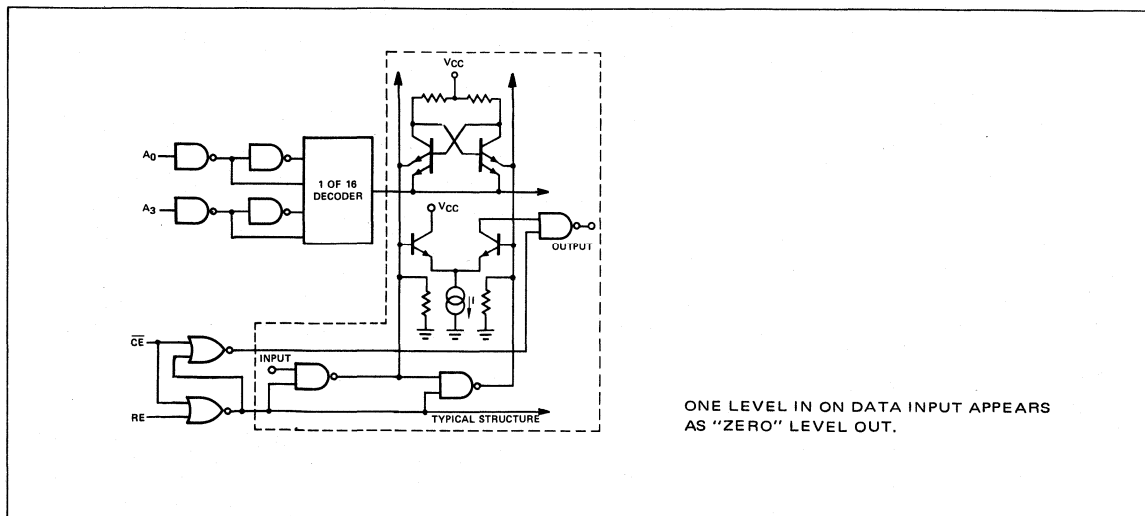
SWITCHING CHARACTERISTICS  $0 \leq T_A \leq 75^\circ\text{C}$ ,  $4.75 \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
Minimum Write Pulse Width ( $W_{pW}$ )	30	18		ns	See Note 12 $T_A = 25^\circ\text{C}$ , See Note 12
Input Setup Time ( $I_{SU}$ )	20	18		ns	
Input Hold Time ( $I_{HO}$ )	10	0		ns	
Address Setup Time ( $A_{SU}$ )	10			ns	
Address Hold Time ( $A_{HO}$ )	10			ns	
Access Time ( $T_A$ )			60	ns	
Access Time ( $T_A$ )		35	50	ns	
Data Pulse Width ( $D_{pW}$ )	20			ns	
Write Recovery Time ( $T_{WR}$ )		25	40	ns	
Write Access Time ( $T_{WA}$ )		25	50	ns	
Chip Enable Recovery Time ( $T_{CR}$ )		20	35	ns	
Chip Enable Access Time ( $T_{CA}$ )		20	35	ns	

NOTES

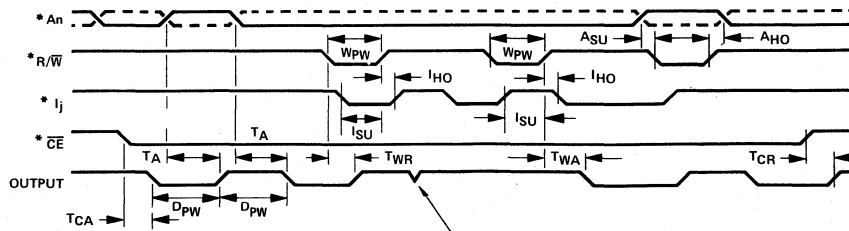
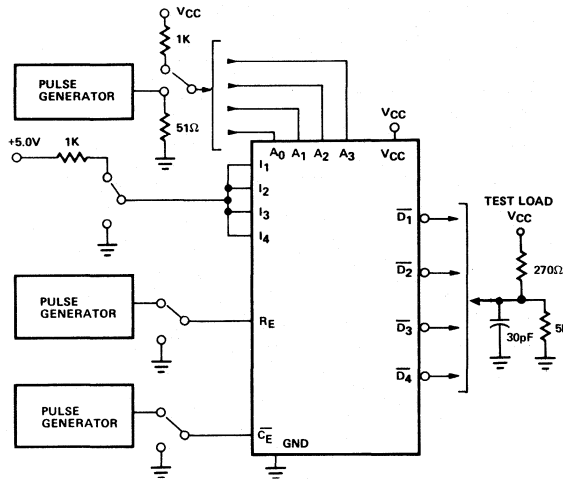
1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current is defined as into the terminal referenced.
4. Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
5.  $V_{CC} = 5.0\text{V}$ .
6. Output sink current is supplied through a resistor to  $V_{CC}$ .
7. One DC fan-out is defined as 0.8mA.
8. By DC tests per the truth table, all inputs have guaranteed thresholds of 0.8V for logical "0" and 2.0V for logical "1".
9. For any given binary code on the Address inputs the Write input must be momentarily brought to a logical "0" level.
10. All sense outputs in "0" state.
11. Test each input one at a time.
12. Address Pulse Width ( $A_{pW}$ ) is 40ns for this test.
13. Rise and fall times of inputs for AC tests are  $\leq 5\text{ns}$ . Pulse amplitudes are 2.5 volts and measurements are made at 1.5 volts.

FUNCTIONAL DIAGRAM



ONE LEVEL IN ON DATA INPUT APPEARS AS "ZERO" LEVEL OUT.

AC TEST FIGURES AND WAVEFORMS



NOTE: NEGATIVE TRANSITION DOES NOT GO BELOW 2.6 VOLTS AND GENERALLY IS NOT MEASURABLE.

\* See Note 13.



### DIGITAL 8000 SERIES TTL/MEMORY

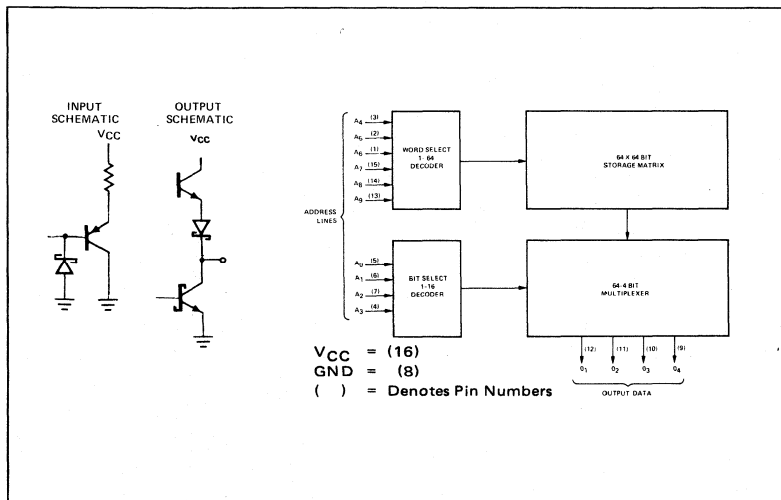
#### DESCRIPTION

The 8228 is a 4096 Bit Bipolar Read Only Memory organized as 1024 words by 4 bits per word. Available in a 16 pin dual in-line package, the 8228 can provide very high bit packing density by replacing four standard 256X4 ROMS.

The 8228 is fully TTL compatible and includes on-the-chip decoding. Typical access time is 50ns with a power consumption of only .125mW per bit.

The standard 8228 ROM pattern is the USASCII Row Character Generator code; however, custom patterns are also available. The standard pattern is specified as N8228I - CD162, while custom circuits are identified as N8228I - CXXX. A truth table/order blank is included on page 4-46 for ordering custom patterns.

#### BLOCK DIAGRAM



See page 4-35 for CD162 Pattern and USASCII Row Character Generator.

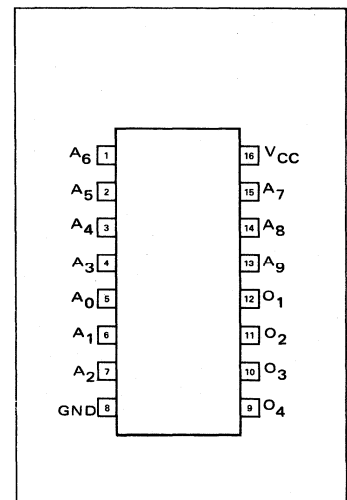
#### FEATURES

- BUFFERED ADDRESS LINES
- ON THE CHIP DECODING
- TOTEM POLE OUTPUTS
- DIODE PROTECTED INPUTS
- 16 PIN PACKAGE (1/3 SIZE OF 24 PIN PACKAGE)

#### APPLICATIONS

- MICROPROGRAMMING
- HARDWIRED ALGORITHMS
- CHARACTER RECOGNITION
- CHARACTER GENERATION
- CONTROL STORE

#### PIN CONFIGURATION



$$0^{\circ}\text{C} \leq T_A \leq 75^{\circ}\text{C}; 4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"0" Output Voltage	2.7	-10	0.5	V	I <sub>out</sub> = 11.2 mA I <sub>out</sub> = -1.0 mA V <sub>in</sub> = 0.45V V <sub>in</sub> = 5.5V	
"1" Output Voltage			0.5	V		
"0" Input Current			-400	μA		
"1" Input Current		1	25	μA		
Input Threshold Voltage			.85	V		
"0" Level	2.0			V		
"1" Level				V		

**SIGNETICS 4096-BIT ROM ■ 8228**

**ELECTRICAL CHARACTERISTICS (Cont'd)**

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Input Clamp Voltage	-1.2			V	$I_{in} = -18\text{mA}$ $O_1 \text{ to } O_3 = "0"$ $V_{OUT} = 0 \text{ Volts}$	
Power Consumption		140	170	mA		
Output Short Circuit Current	-20		-70	mA		

**SWITCHING CHARACTERISTICS  $0 \leq T_A \leq 75^\circ\text{C}$ ,  $4.75 \leq V_{CC} \leq 5.25\text{V}$**

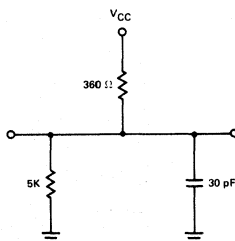
CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
Access Time—Address to Output		50	70	ns		5

**NOTES**

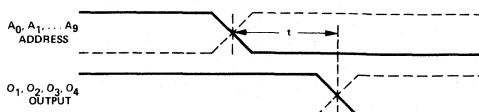
1. Positive current is defined as into the terminal referenced.
2. No more than one output should be grounded at the same time.
3. Manufacturer reserves the right to make design and process changes and improvements.
4. Applied voltages must not exceed 6.0V. Input currents must not exceed  $\pm 30\text{mA}$ . Output currents must not exceed  $\pm 100\text{mA}$ . Storage temperature must be between  $-60^\circ\text{C}$  to  $+150^\circ\text{C}$ .
5. Rise and fall time for this test must be less than 5ns. Input amplitudes are 2.8V and all measurements are made at 1.5V.

**AC TEST FIGURE AND WAVEFORM**

**TEST LOAD**



**READ CYCLE**



### DESCRIPTION

The 82S06 and 82S07 are ideal devices for use in Control Stores, small buffers, scratch pads, "cache" type buffer stores, memory maps, etc. The typical read time (the time between applying an address and obtaining valid output data) is 45ns. The typical write time (the time between applying one address and storing data) is 30ns. The circuit has 3 chip enable inputs which greatly simplifies the circuit configuration when used in large memories. The 82S06 and 82S07 also feature very low input loadings, 25 microamperes for a "1" state and -100 microamperes for "0".

The memories are TTL compatible and operate from single 5 volt supply.

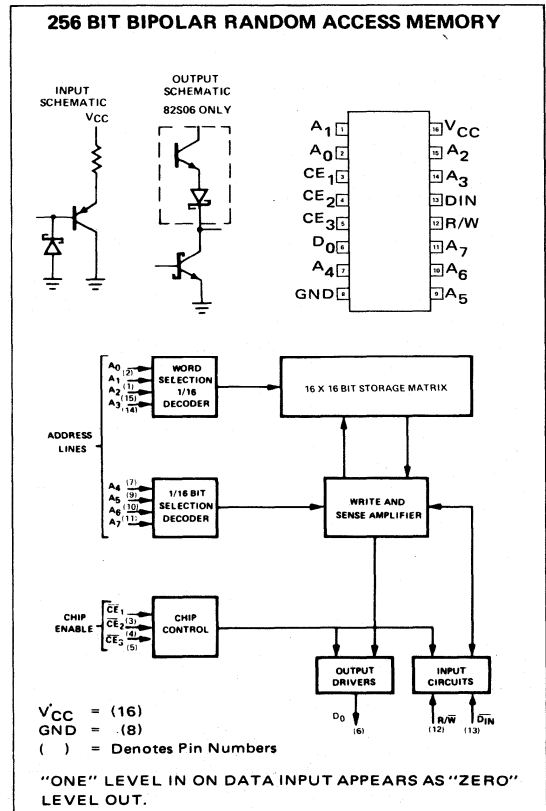
### APPLICATIONS

- BUFFER MEMORY
- WRITABLE CONTROL STORE
- MEMORY MAPPING
- PUSH DOWN STACK

### FEATURES

- 256 X 1 ORGANIZATION
- 30 NANOSECOND ACCESS TIME TYPICAL
- LOW 1.5 mw/BIT POWER DISSIPATION TYPICAL
- LOW 100  $\mu$ A INPUT LOADING
- TRI-STATE (82S06) OR OPEN COLLECTOR (82S07) OUTPUT
- ON CHIP DECODING

### BLOCK DIAGRAM



### ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 0 to 75°C, V<sub>CC</sub> = 5.0V ±5) Note 1, 2, 3

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"0" Input Current		-10	-100	$\mu$ A	V <sub>in</sub> = 0.45V	
"1" Input Current		<1.0	25	$\mu$ A	V <sub>in</sub> = 5.5V	
"0" Output Voltage		0.35	0.45	V	I <sub>out</sub> = 16mA	
Output Leakage Current (82S07)		<1.0	40	$\mu$ A	CE <sub>1</sub> , CE <sub>2</sub> , CE <sub>3</sub> = "1", V <sub>out</sub> = 5.5V	
Output "off" Current (82S06)		<1.0	±100	$\mu$ A	CE <sub>1</sub> , CE <sub>2</sub> , CE <sub>3</sub> = "1", 0.45 ≤ V <sub>out</sub> ≤ 5.5V	
"1" Output Voltage (82S06)	2.6			V	CE <sub>1</sub> = CE <sub>2</sub> = CE <sub>3</sub> = "0" I <sub>out</sub> = -3.2mA	
"0" Input Threshold			0.85	V		
"1" Input Threshold	2.0		2.0	V		
Power Consumption		80/400	115/604	mA/mW		
Input Clamp Voltage	-1.2	-0.8		V	I <sub>in</sub> = -18mA	
Input Capacitance		5.0		pF		
Output Capacitance		8.0		pF		
Output Short Circuit Current (82S06)	-20		-70	mA	V <sub>out</sub> = 0V	

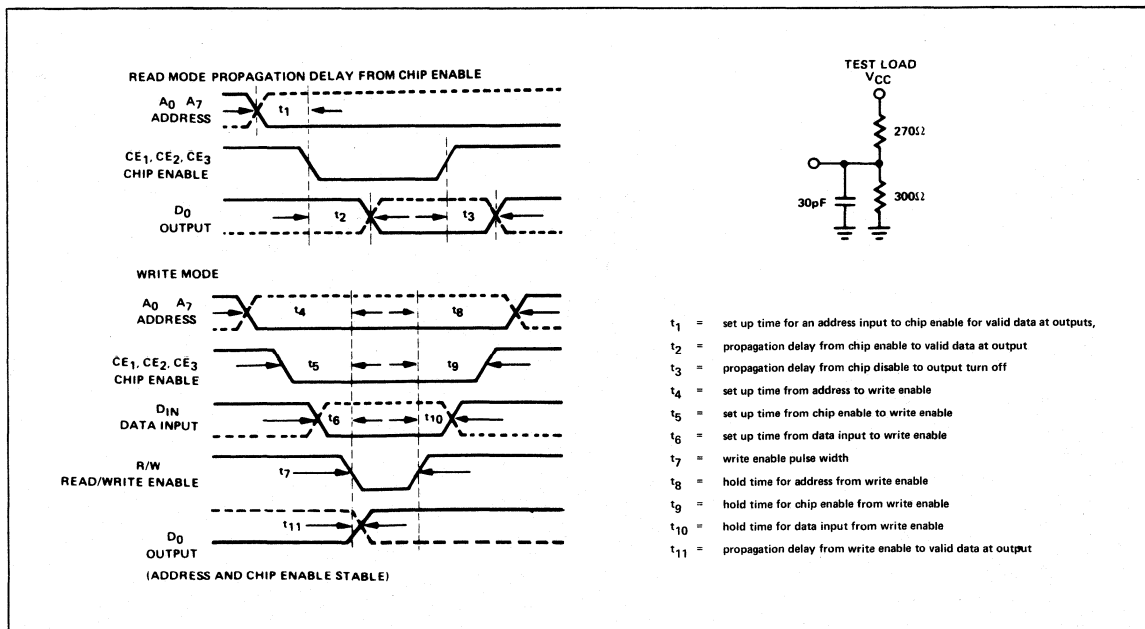
SWITCHING CHARACTERISTICS  $0 \leq T_A \leq 75^\circ\text{C}$ ,  $4.75 \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES		
	MIN.	TYP.	MAX.	UNITS				
Access Time—Address to Output		45	65	ns	$T_A = 25^\circ\text{C}$ Only	4,5		
Access Time—Address to Output			80	ns				
Address Set-Up Time (read)	$t_1$	25	10	80			ns	
Propagation Delay								4,5
Chip Enable to Output Enable	$t_2$		25	40			ns	4,5
Propagation Delay								4,5
Chip Enable to Output Disable	$t_3$		25	40			ns	4,5
Address to Write Enable								4,5
Set-Up Time	$t_4$	25	5				ns	4,5
Chip Enable to Write Enable								4,5
Set-Up Time	$t_5$	10	0				ns	4,5
Data Input to Write Enable						4,5		
Set-Up Time	$t_6$	10	0		ns	4,5		
Write Enable Pulse Width	$t_7$	30	15		ns	4,5		
Address Hold Time	$t_8$	10	0		ns	4,5		
Chip Enable Hold Time	$t_9$	10	0		ns	4,5		
Data Input Hold Time	$t_{10}$	10	0		ns	4,5		
Write Enable Propagation Delay	$t_{11}$		30	40	ns	4,5		

NOTES

1. Positive current is defined as into the terminal referenced
2. Manufacturer reserves the right to make design and process changes and improvements.
3. Applied voltages must not exceed 6.0V. Input currents must not exceed  $\pm 30\text{mA}$ . Output currents must not exceed  $\pm 100\text{mA}$ . Storage temperature must be between  $-60^\circ\text{C}$  to  $+150^\circ\text{C}$ .
4. Refer to Timing Diagram for definition of terms and test load.
5. Rise and fall times for this test must be less than 5ns. Input amplitudes are 2.8V and all measurements are made at 1.5 volts.

TIMING DIAGRAM



#### DESCRIPTION

The 82S12/112 is a Schottky TTL 32 bit multipoint memory organized in 8 words of 4 bits each. The device is ideally suited for high speed accumulators and buffer memories.

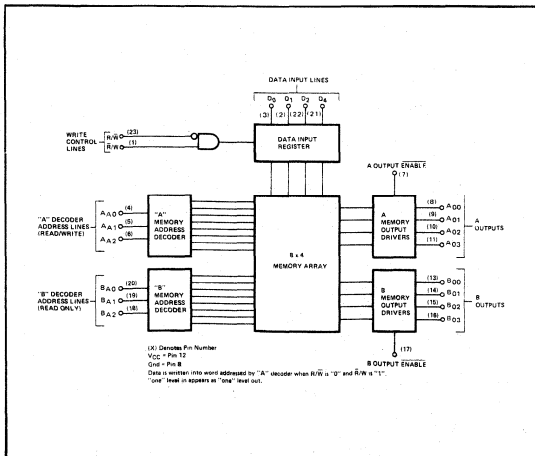
Stored data is addressed through 2 independent sets of 3-input decoders, and read out when the corresponding output enable line is low. Two separate word locations can, therefore, be read at the same time by enabling both the A and B output drivers. In addition, data can be read and written at the same time by utilizing the "A" address to specify the location of the word to be written, and the "B" address to specify the word to be read.

The 82S12/112 can be used in larger memory arrays since it includes all the control logic required to disable the chip and the outputs are open-collector devices suitable for "Wire-ORing."

#### FEATURES

- LOW CURRENT INPUT BUFFERS ( $-25\mu\text{A}$  TYPICAL)
- SEPARATE INPUT DECODERS FOR EACH WORD
- SEPARATE OUTPUT ENABLE LINES FOR EACH WORD
- OPEN COLLECTOR (82S12) OR TRI-STATE (82S112) OUTPUTS
- 2 WRITE ENABLE LINES
- FAST ACCESS (20 ns TYPICAL)
- USEFUL 8 X 4 ORGANIZATION
- TTL COMPATIBLE
- NON INVERTING DATA LINES

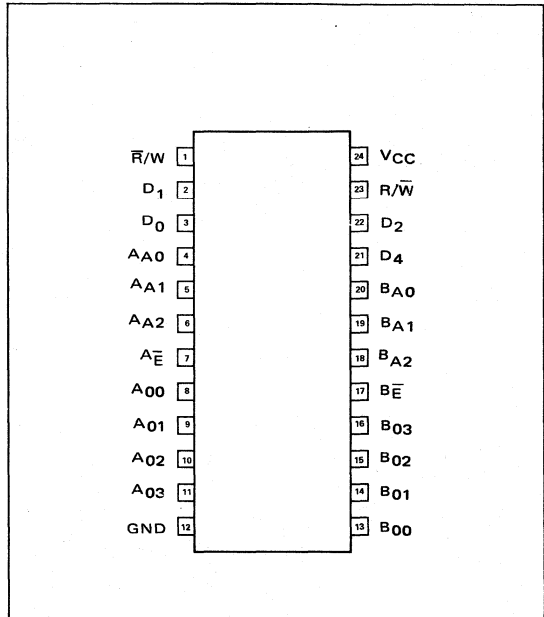
#### BLOCK DIAGRAM



#### APPLICATIONS

- SCRATCH PAD MEMORY
- BUFFER MEMORY
- ACCUMULATOR REGISTER
- GENERAL REGISTER

#### PIN CONFIGURATION



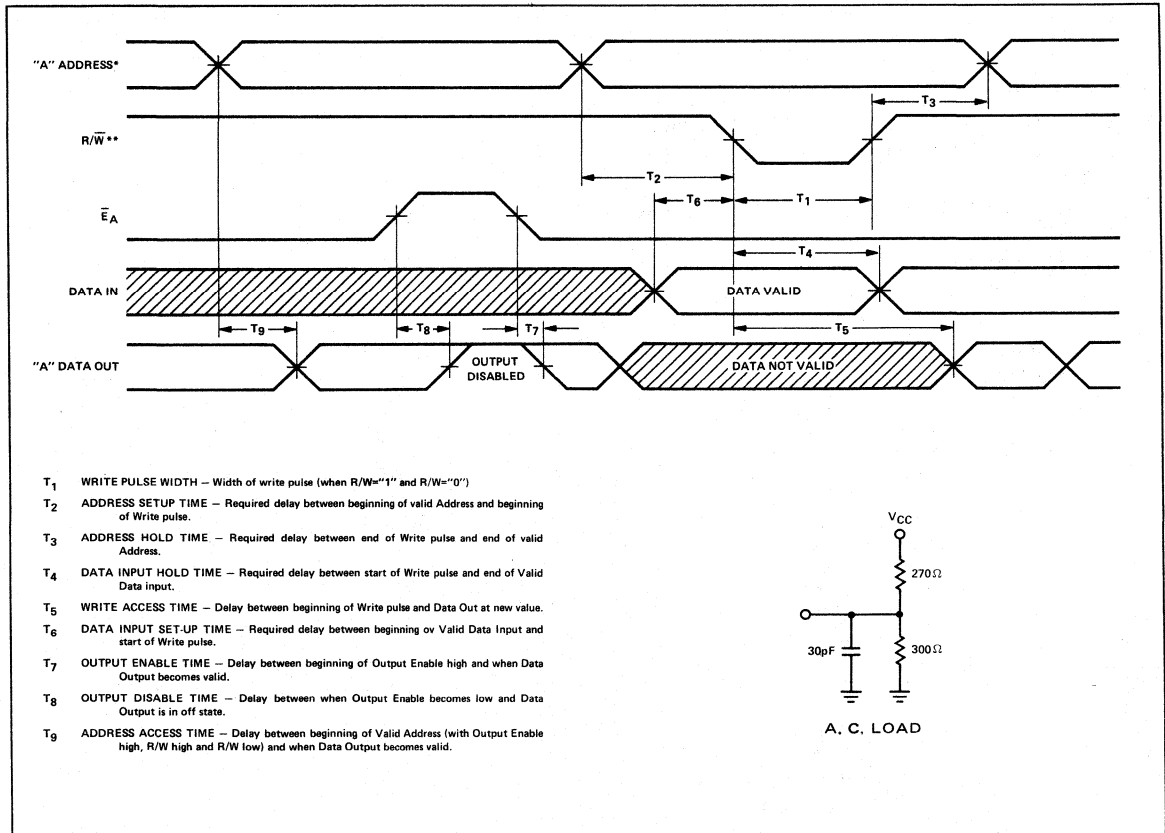
#### TRUTH TABLE

R/W	R/W-bar	A OUTPUT ENABLE	B OUTPUT ENABLE	MODE	OUTPUTS	
					A	B
0	X	1	1	Outputs Disabled	"1"	"1"
0	X	1	0	Read	"1"	Data
0	X	0	1	Read	Data	"1"
0	X	0	0	Read	Data	Data
1	1	1	1	Read	"1"	"1"
1	1	1	0	Read	"1"	Data
1	1	0	1	Read	Data	"1"
1	1	0	0	Read	Data	Data
1	0	1	1	Write	"1"	"1"
1	0	1	0	Write	"1"	Data
						"B" Address
1	0	0	1	Write	Data	"1"
1	0	0	0	Write	Data	Data
					Being	Written
					Address	Being
					Written	"B" Address

OBJECTIVE ELECTRICAL SPECIFICATIONS  $0^{\circ}\text{C} \leq T_A \leq 75^{\circ}\text{C}$ ;  $-4.75\text{ V} \leq V_{CC} \leq 5.25\text{ V}$ .

CHARACTERISTICS	LIMITS			UNITS	TEST CONDITIONS
	MIN.	TYP.	MAX.		
Input "0" Current			-250	$\mu\text{A}$	$V_{in} = 0.45\text{ V}$ $V_{in} = 5.5\text{ V}$
Input "1" Current			25	$\mu\text{A}$	
Input "0" Threshold Voltage			0.85	V	
Input "1" Threshold Voltage				V	
Input Clamp Voltage	-1.2			V	$I_{in} = -18\text{ mA}$
Output "0" Current	16			mA	$V_{out} = 0.5\text{ V}$
Output "0" Current	9.6				$V_{out} = 0.45\text{ V}$
Output "1" Voltage (82S112)	2.6			Volts	$I_{out} = -3.2\text{ mA}$
Output Off Current (82S12)			40	$\mu\text{A}$	$V_{out} \leq 5.5\text{ V}$
Output Off Current (82S112)	-40		+40	$\mu\text{A}$	$0.45 \leq V_{out} \leq 5.5\text{ V}$
Power Consumption		110/550	160/840	mA/mW	Outputs Enabled
Write Pulse Width	$T_1$	30	15	ns	$T_A = 25^{\circ}\text{C}$ Only
Address Set Up Time	$T_2$	45			
Address Hold Time	$T_3$		10	ns	
Data Input Hold Time	$T_4$		0	ns	
Write Access Time	$T_5$		0	ns	
Data Input Set Up Time	$T_6$		30	ns	
Output Enable Time	$T_7$		5	ns	
Output Disable Time	$T_8$		10	ns	
Address Access Time	$T_9$		10	ns	
			20	ns	
			20	ns	
			30	ns	

TIMING DIAGRAM



NOTES

- \*\*"B" Address functions identically in read mode. No write mode through B address decoder.
- \*\*R/W input is either the reverse of R/W or held high.
- Outputs can be disabled during write cycle to penetrate a known output state during write.

### DESCRIPTION

The 82S16 and 82S17 are ideal devices for use in Control Stores, small buffers, scratch pads, "cache" type buffer stores, memory maps, etc. The typical read time (the time between applying an address and obtaining valid output data) is 30ns. The typical write time (the time between applying one address and storing data) is 30ns. The circuit has 3 chip enable inputs which greatly simplifies the circuit configuration when used in large memories. The 82S16 and 82S17 also feature very low input loadings, 25 microamperes for a "1" state and -100 microamperes for "0".

The memories are TTL compatible and operate from single 5 volt supply.

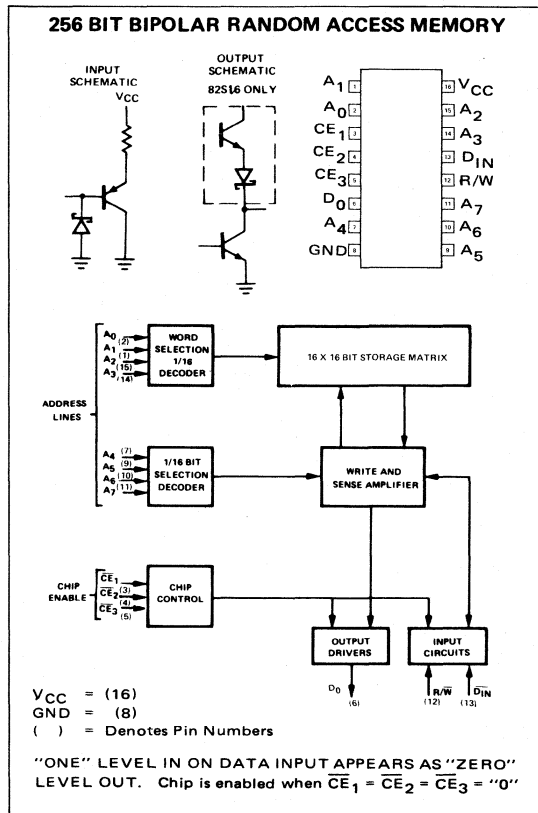
### APPLICATIONS

**BUFFER MEMORY  
WRITABLE CONTROL STORE  
MEMORY MAPPING  
PUSH DOWN STACK**

### FEATURES

- 256 X 1 ORGANIZATION
- 30 NANOSECOND ACCESS TIME TYPICAL
- LOW 1.5 mw/BIT POWER DISSIPATION TYPICAL
- LOW 100  $\mu$ A INPUT LOADING
- TRI-STATE (82S16) OR OPEN COLLECTOR (82S17) OUTPUT
- ON CHIP DECODING

### BLOCK DIAGRAM



### ELECTRICAL CHARACTERISTICS (0°C ≤ T<sub>A</sub> ≤ 75°C ; 4.75V ≤ V<sub>CC</sub> ≤ 5.25V) Note 1, 2, 3

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"0" Input Current		-10	-100	$\mu$ A	V <sub>in</sub> = 0.45V	
"1" Input Current		<1.0	25	$\mu$ A	V <sub>in</sub> = 5.5V	
"0" Output Voltage		.35	0.45	V	I <sub>out</sub> = 16mA	
Output Leakage Current (82S17)		<1.0	40	$\mu$ A	$\overline{CE}_1, \overline{CE}_2, \overline{CE}_3 = "1"$ , V <sub>out</sub> = 5.5V	
Output "off" Current (82S16)		<1.0	40	$\mu$ A	$\overline{CE}_1, \overline{CE}_2, \overline{CE}_3 = "1"$ , 0.45 ≤ V <sub>out</sub> ≤ 5.5V	
"1" Output Voltage (82S16)				V	$\overline{CE}_1 = \overline{CE}_2 = \overline{CE}_3 = "0"$ , I <sub>out</sub> = -3.2mA	
"0" Input Threshold	2.6			V		
"1" Input Threshold	2.0			V		
Power Consumption		80/400	115/604	mA/mW		
Input Clamp Voltage	-1.2	.8		V	I <sub>in</sub> = -18mA	
Input Capacitance		5		pF		
Output Capacitance		8		pF		
Output Short Circuit (82S16)	-20		-70	mA	V <sub>out</sub> = 0V	

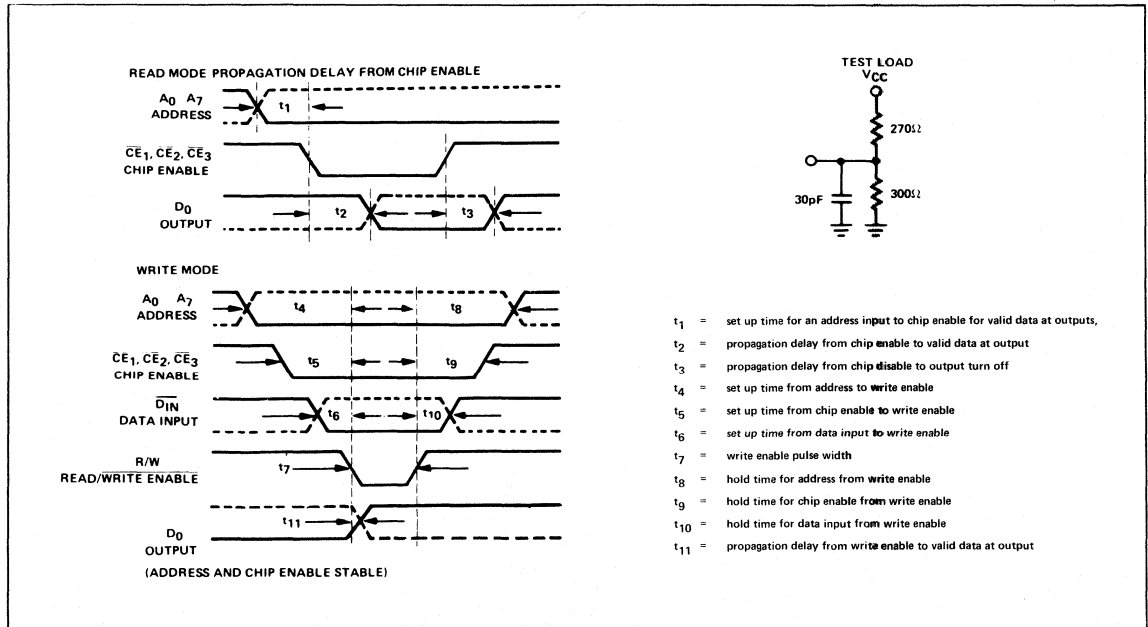
SWITCHING CHARACTERISTICS  $0 \leq 75^{\circ}\text{C}$ ,  $4.75 \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS		LIMITS				TEST CONDITIONS	NOTES	
		MIN.	TYP.	MAX.	UNITS			
Access Time—Address to Output			30	50	ns	$T_A = 25^{\circ}\text{C}$ Only	4,5	
Access Time—Address to Output				60				
Address Set-Up Time (read)	$t_1$	25	10	65	ns			
Propagation Delay								4,5
Chip Enable to Output Enable	$t_2$		20	40	ns			
Propagation Delay								4,5
Chip Enable to Output Disable	$t_3$		20	40	ns			
Address to Write Enable								4,5
Set-Up Time	$t_4$	20	5		ns			
Chip Enable to Write Enable								4,5
Set-Up Time	$t_5$	10	0		ns			
Data Input to Write Enable						4,5		
Set-Up Time	$t_6$	10	0		ns			
Write Enable Pulse Width	$t_7$		30	15	ns	4,5		
Address Hold Time	$t_8$	0	0		ns	4,5		
Chip Enable Hold Time	$t_9$	0	0		ns	4,5		
Data Input Hold Time	$t_{10}$	0	0		ns	4,5		
Write Enable Propagation Delay	$t_{11}$		30	40	ns	4,5		
Output Short Circuit Current (82S16)		-20		-70	mA	$V_{out} = 0\text{V}$	4,5	

NOTES:

1. Positive current is defined as into the terminal referenced.
2. Manufacturer reserves the right to make design and process changes and improvements.
3. Applied voltages must not exceed 6.0V, Input currents must not exceed 30mA, Output currents must not exceed 100mA, Storage temperature must be between  $-60^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$ .
4. Refer to Timing Diagram for definition of terms and test load.
5. Rise and fall times for this test must be 5ns. Input amplitudes are 2.8V and all measurements are made at 1.5 volts.

TIMING DIAGRAM





### DIGITAL 8000 SERIES TTL/MEMORY

#### DESCRIPTION

The 82S21 is a TTL 64 bit Write-While-Read Random Access Memory organized in 32 words of 2 bits each. The 82S21 is ideally suited for high speed buffers and as the memory element in high speed accumulators.

Words are selected through a 5 input decoder when the Read-Write enable input,  $\overline{CE}$  is at logic "1".  $\overline{W_0}$  and  $\overline{W_1}$  are the write inputs for bit 0 and bit 1 of the word selected.  $\overline{C}$  is the write control input. When  $\overline{W_X}$  and  $\overline{C}$  are both at logic "0" data on the  $I_0$  and  $I_1$  data lines are written into the addressed word. The read function is enabled when either  $\overline{W_X}$  or  $\overline{C}$  is at logic "1".

An internal latch is on the chip to provide the Write-While-Read capability. When the latch control line,  $\overline{L}$ , is logic "1" and data is being read from the 82S21, the latch is effectively bypassed. The data at the output will be that of the addressed word. When  $\overline{L}$  goes from a logic "1" to logic "0" the outputs are latched and will remain latched regardless of the state of any other address or control line. When  $\overline{L}$  goes from "0" to "1" the outputs unlatch and the outputs will be that of the present address word.

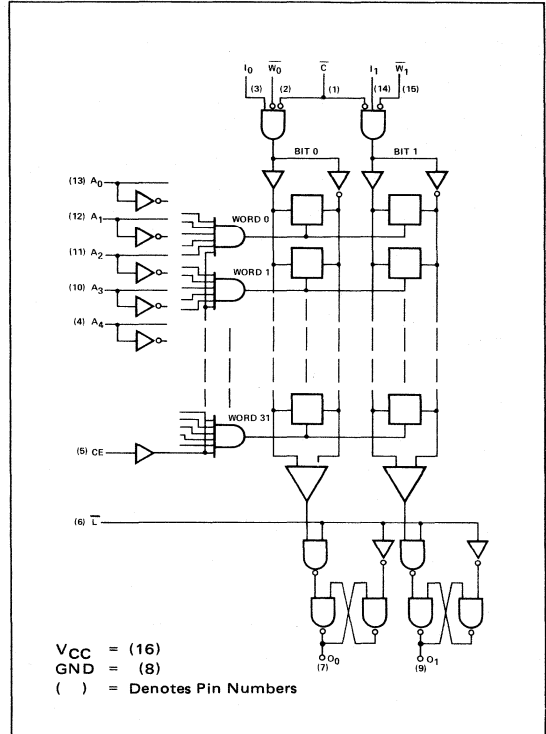
#### FEATURES

- BUFFERED ADDRESS LINES
- ON CHIP LATCHES
- ON CHIP DECODING
- BIT MASKING CONTROL LINES
- ENABLE CONTROL LINE
- OPEN COLLECTOR OUTPUTS WITH 40mA CAPABILITY
- PROTECTED INPUTS
- VERY HIGH SPEEDS (25ns TYP)

#### APPLICATIONS

- SCRATCH PAD MEMORY
- BUFFER MEMORY
- ACCUMULATOR REGISTER
- CONTROL STORE

#### LOGIC DIAGRAM



#### TRUTH TABLE

CE	$\overline{C}$	$\overline{W_0}$	$\overline{W_1}$	$\overline{L}$	Mode	Outputs
X	X	X	X	0	Output Hold	Data from last addressed word when $\overline{CE} = "1"$
0	X	X	X	1	Read & Write Disabled	Disabled logic "1"
1	1	X	X	X	Read	Data stored in addressed word
1	0	1	1	X	Read	Data stored in addressed word
1	0	0	0	0	Write Data	Data from last word address when $\overline{L}$ went from "1" to "0"
1	0	0	0	1	Write Data	Data being written into memory
1	0	0	1	X	Write Data into Bit 0 Only	If $\overline{L} = 0$ : Data from last word address when $\overline{L}$ went from "1" to "0"
1	0	1	0	X	Write Data into Bit 1 Only	If $\overline{L} = 1$ : Data being written into the selected bit location and stored in other addressed location

# SIGNETICS 64-BIT HIGH SPEED WRITE-WHILE-READ ROM ■ 82S21

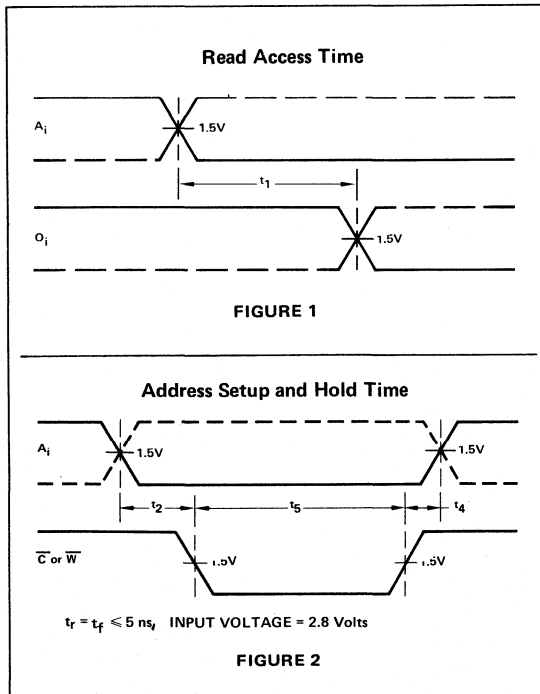
## ELECTRICAL CHARACTERISTICS $0^{\circ}\text{C} \leq T_A \leq 75^{\circ}\text{C}; 4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"0" Output Voltage			.45	V	$V_{out} = 40\text{mA}$ $V_{out} = 5.5\text{V}$	
"1" Output Leakage Current			40	$\mu\text{A}$		
"0" Input Current (All Inputs)			-1.6	mA	$V_{in} = 0.45\text{V}$ $V_{in} = 5.5\text{V}$	
"1" Input Current (All Inputs)			25	$\mu\text{A}$		
Input "0" Threshold Voltage			0.85	V		
Input "1" Threshold Voltage	2.0			V		
Power Consumption			130/683	mA/mW		
Input Clamp Voltage	-1.2					

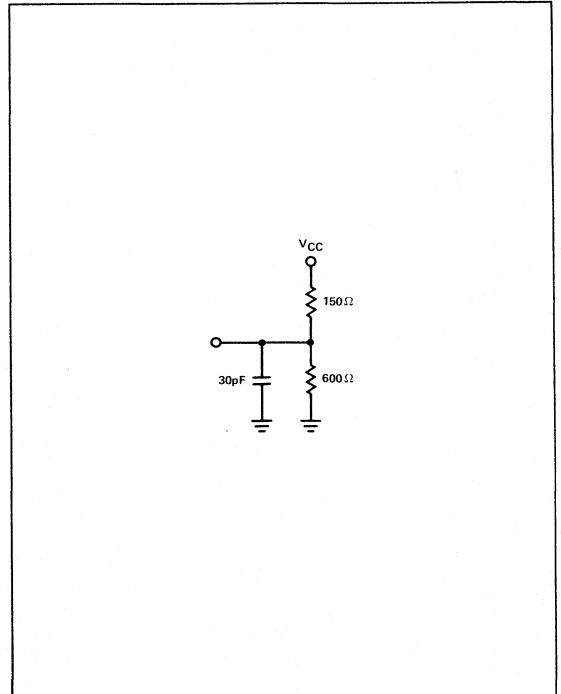
## SWITCHING CHARACTERISTICS $0 \leq T_A \leq 75^{\circ}\text{C}, 4.75 \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS		LIMITS				TEST CONDITIONS	NOTES
		MIN.	TYP.	MAX.	UNITS		
Read Access Time Address to Output	$t_1$		25	50	ns		
Address Set-Up Time	$t_2$	15	8		ns		
Data Set-Up Time	$t_3$	20	15		ns		
Address Hold Time	$t_4$	0			ns		
Control or Write Pulse Width	$t_5$	20	15		ns		
Write Access Time	$t_6$		20	25	ns		
Address to Latch Set-Up Time	$t_7$		25	50	ns		
Latch Address to Address Hold Time	$t_8$	10	7		ns		
Delatch Access Time	$t_9$		15	25	ns		
Data Hold Time Earliest	$t_{10}$	5	0		ns		

### AC WAVEFORM



### TEST LOAD



AC WAVEFORMS

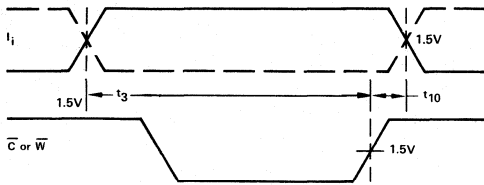


Fig. 3 Data Setup and Hold Time

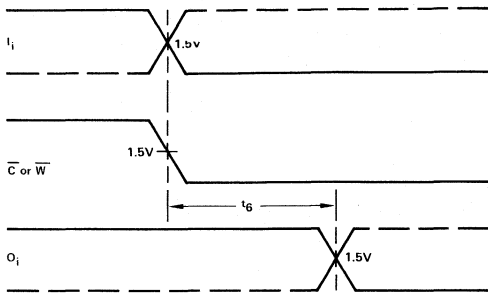


Fig. 4 Write Access Time

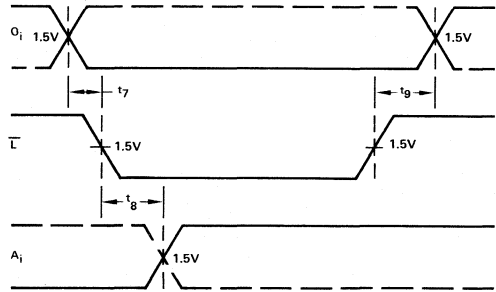
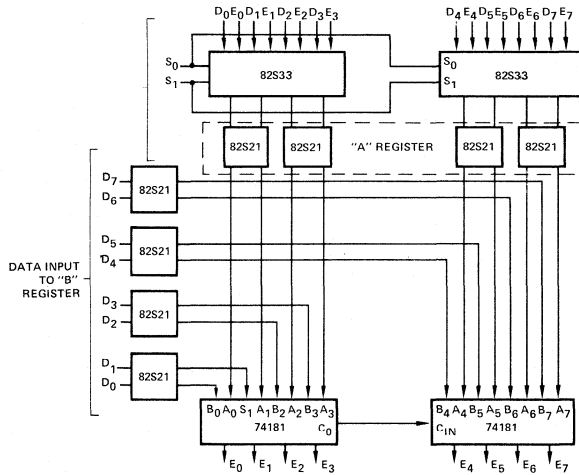


Fig. 5 Latch Times

TYPICAL APPLICATION



BASIC 8 BIT FULLY BUFFERED ACCUMULATOR

By use of the control lines  $S_0$  and  $S_1$  data is loaded into the "A" register through inputs  $D_X$  or from the outputs of the 74181's ( $E_X$ ) to the 82S33's and stored in the 82S21's organized as a 32 x 8 RAM register. Data is loaded directly into the "B" register. With this arrangement, the function  $A+B \rightarrow A$  (A plus B into A) can be performed in 70ns, typically, starting from data stored in the 82S21's.

### OBJECTIVE SPECIFICATION

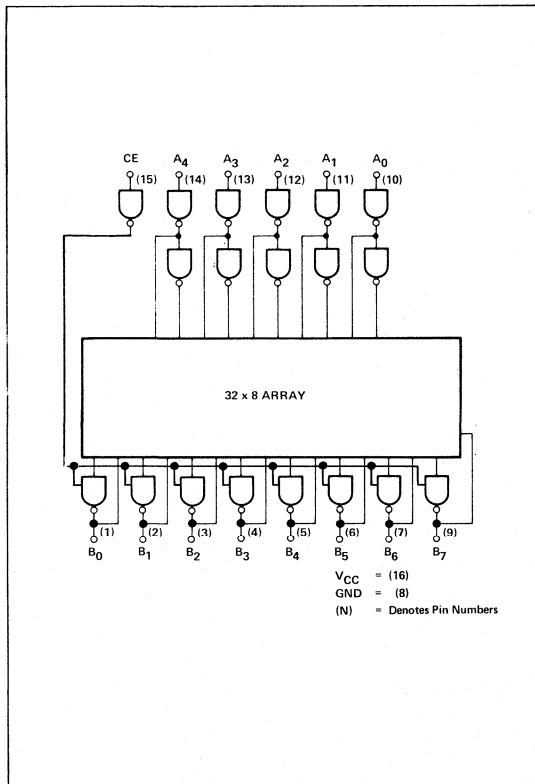
#### DESCRIPTION

The 82S23 (open Collector Outputs) and the 82S123 (Tristate Outputs) are Bipolar 256 Bit Read Only Memories organized as 32 words by 8 bits per word. They are Field-Programmable, which means that custom patterns are immediately available by following the simple fusing procedure given in this data sheet. A chip enable line is provided and the outputs are bare collector or Tristate to allow for memory expansion capability.

The 82S23 and 82S123 are fully TTL compatible and include on-the-chip decoding. Typical access time is 35 nS.

The standard 82S23 and 82S123 are supplied with all outputs at a logical "0." If a programmed unit is required the Truth Table/Order Blank on page 4-43 of the TTL MSI/Memory Handbook may be used.

#### LOGIC DIAGRAM



### DIGITAL 8000 SERIES TTL/MEMORY

#### FEATURES

- PNP INPUTS
- BUFFERED ADDRESS LINES
- ON THE CHIP DECODING
- A CHIP ENABLE LINE
- OPEN COLLECTOR OR TRISTATE OUTPUTS
- DIODE PROTECTED INPUTS
- NO SEPARATE "FUSING" PINS
- BOARD PROGRAMMABLE

#### APPLICATIONS PROTOTYPING

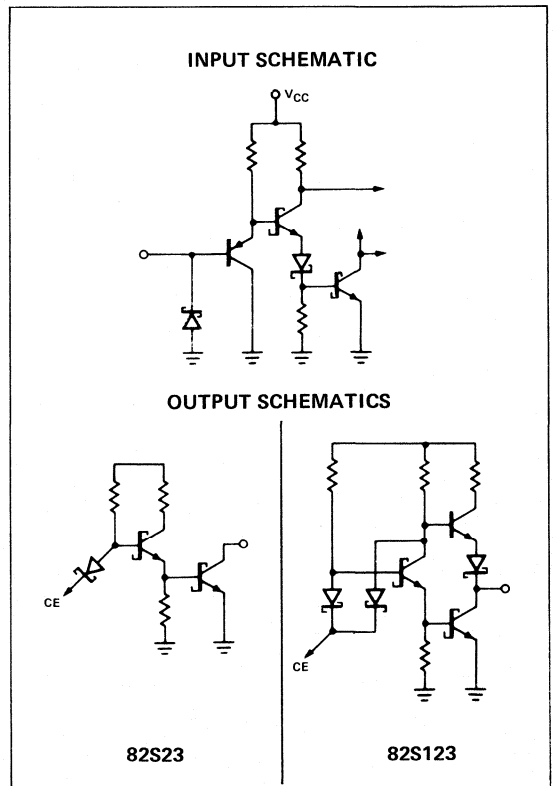
#### VOLUME PRODUCTION

#### MICROPROGRAMMING

#### HARDWIRED ALGORITHMS

#### CONTROL STORE

#### INPUT/OUTPUT SCHEMATIC DIAGRAMS



SWITCHING CHARACTERISTICS  $0 \leq T_A \leq 75^\circ\text{C}$ ,  $4.75 \leq V_{CC} = 5.25\text{V}$ 

CHARACTERISTICS	LIMITS				TEST CONDITIONS	NOTES
	MIN.	TYP.	MAX.	UNITS		
"0" Output Voltage			0.5	V	$I_{out} = 20\text{mA}$	
"0" Output Voltage			0.45	V	$I_{out} = 9.6\text{mA}$	
"1" Output Leakage			40	$\mu\text{A}$	CE = "1" $V_{out} = 5.5\text{V}$	12
82S23			100	$\mu\text{A}$	CE = "0" $V_{out} = 5.5\text{V}$	12
82S123	-40		+40	$\mu\text{A}$	$V_{out} = 0.5\text{V}/V_{out} = 5.5\text{V}$	12
"1" Output Current 82S123	-2.0			mA	$V_{out} = 2.4\text{V}$ , CE = "0"	After Fusing
"0" Input Current			-250	$\mu\text{A}$	$V_{in} = 0.45\text{V}$	
"1" Input Current			50	$\mu\text{A}$	$V_{in} = 5.5\text{V}$	
Input Threshold Voltage						
"0" Level	.85			V		
"1" Level			2.0	V		
Propagation Delay						
Address to Output		35	50	ns	$T_A = 25^\circ\text{C}$ only	
Enable to Output		15	30	ns	$T_A = 25^\circ\text{C}$ only	
Input Calmp Voltage	-1.2		35	ns		
Power Consumption				V	$I_{in} = -18\text{mA}$	
82S23		80/400	115/605	mA/mW		
82S123		80/400	115/605	mA/mW		
Output Short Circuit Current	20		90	mA	$V_{out} = 0\text{V}$	

## NOTES

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current is defined as into the terminal referenced.
- Positive logic definition: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- One DC fan-out is defined as 0.8mA.
- One AC fan-out is defined as 50pF.
- Manufacturer reserves the right to make design and process changes and improvements.
- By DC tests per the truth table, all inputs have guaranteed thresholds of 0.8V for logical "0" and 2.0V for logical "1".
- For detailed conditions, see AC testing.
- Connect an external 1k resistor from  $V_{CC}$  to the output terminal for this test.

## OBJECTIVE FUSING PROCEDURE

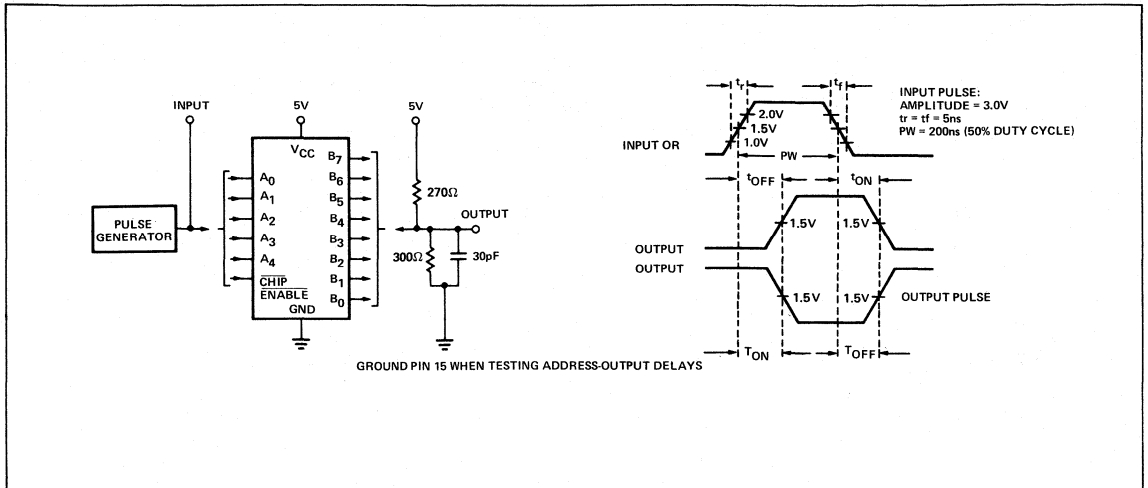
The 82S23/82S123 standard part is shipped with all outputs at Logical "0". To write a Logical "1" proceed as follows:

- GND Pin 8 and apply 5V to  $V_{CC}$ , Pin 16.
- Remove any load from the outputs.
- Ground the Chip Enable.
- Address the desired location by applying ground for a "0" and  $5.0 \pm 0.25\text{V}$  for a "1" at the address input lines.
- Raise  $V_{CC}$  to  $10.0\text{V} \pm 0.5\text{V}$ .
- Apply  $65 \pm 3\text{mA}$  to the output to be programmed to logic "1". (The voltage will be between 12 to 18V until fused, and must be clamped at 20.0V max.)
- Release fusing current.
- Reduce  $V_{CC}$  to 5.0V.
- Proceed to the next output and repeat, or change address and repeat procedure.
- Continue until the entire bit pattern is programmed into your custom 82S23/82S123.

## NOTE:

After 1.0 SEC of programming, a 25% duty cycle on power must be imposed to avoid over heating.

AC TEST FIGURE AND WAVEFORMS



### DIGITAL 8000 SERIES TTL/MEMORY

#### DESCRIPTION

The 82S26 (open Collector Outputs) and the 82S29 (tri State Outputs) are Bipolar 1024 Bit Read Only Memories organized as 256 words by 4 bits per word. They are Field-Programmable, which means that custom patterns are immediately available by following the simple fusing procedure given in this data sheet. Two chip enable lines are provided and the outputs are bussable to allow for memory expansion capability.

The 82S26 and 82S29 are fully TTL compatible and include on-the-chip decoding. Typical access time is 35ns.

The standard 82S26 and 82S29 are supplied with all outputs at a logical "0". If a programmed unit is required the Truth Table/Order Blank on page 4-44/45 can be used.

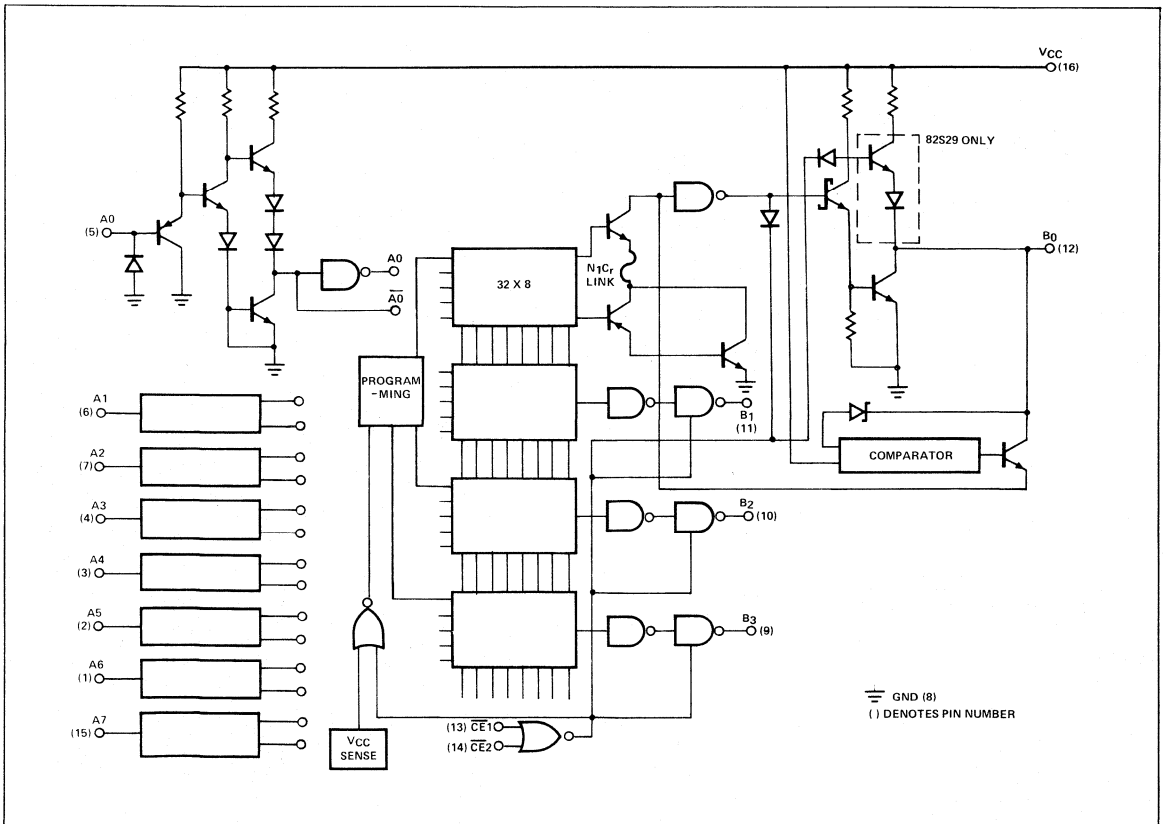
#### APPLICATIONS

PROTOTYPING  
VOLUME PRODUCTION  
MICROPROGRAMMING  
HARDWARE ALGORITHMS  
CONTROL STORE

#### FEATURES

- BUFFERED ADDRESS LINES
- ON THE CHIP DECODING
- TWO CHIP ENABLE LINES
- OPEN COLLECTOR OR TRI STATE OUTPUTS
- DIODE PROTECTED INPUTS
- NO SEPARATE "FUSING" PINS
- UNPROGRAMMED OUTPUTS ARE "0" LEVEL
- BOARD LEVEL PROGRAMMABLE

#### LOGIC DIAGRAM



## PROGRAMMING

### 82S26 AND 82S29 PROGRAMMING PROCEDURE

1. Connect pin 8 (Grnd) to ground.
2. Disable the device by bringing  $\overline{CE}_1$  and/or  $\overline{CE}_2$  to a logical "1" (greater than 2.6 volts). If only one CE pin is used for the control of programming the other CE pin should be at logical "0" (0.4 volts or less).
3. Raise  $V_{CC}$  (pin 16) to  $12.5 \pm 0.5$  volts. (A  $10\mu F$  in parallel with a 200pF high frequency capacitor should be connected between pins 16 and 8, as near the device as possible, to minimize noise on the  $V_{CC}$  line.)
4. Address the word to be programmed, using standard TTL logic levels. Apply  $85 \pm 5mA$  into the output to be programmed to a logical "1". The output must be limited to 22 volts  $\pm 5\%$  and only one output at a time should be programmed.
5. Wait until the current generator has reached the 22 volt clamp. (The current generator will be supplying about 50mA min.) Then drop both  $\overline{CE}_1$  and  $\overline{CE}_2$  to a logical "0" for 2.0msec. (fall time  $\leq 50\mu sec$ ).
6. Return  $\overline{CE}_1$  and/or  $\overline{CE}_2$  to a logical "1" for 10 microseconds.
7. Repeat steps 5, 6, and 7 until the entire word has been programmed. Change address and repeat steps 5, 6, and 7 until the entire device is programmed. At this point  $V_{CC}$  can be dropped to 5.0 volts and the chip enabled so that the outputs can be tested to verify that all bits programmed; if one or more bits have not programmed, return to the proper address and repeat steps 3 to 6 once for each unprogrammed bit.

NOTE: Do not apply the high  $V_{CC}$  (12.5 volts) for greater than 1.0 seconds continuously. At that point use a 20% duty cycle.

### OPERATION OF THE 82S26/82S29 PROGRAMMER

#### INTRODUCTION

Figure 1 shows the complete programmer schematic. The memory to be programmed is inserted, and by means of seven single-pole, double-throw (SPDT) switches, the binary address is selected. Notice that these switches may easily be replaced by thumbwheel switches. The memory outputs

are programmed, one at a time, by means of four double-pole, double-throw (DPDT) switches. This arrangement has the advantage that the switches are normally in the verify mode, indicating the state of the output (logic "0" when not programmed). By switching to the programming position, the outputs may be altered to a logic "1" which will turn on the light emitting diode (LED) indicator. Upon return to the verify position the LED indicator will stay lit for a programmed bit position.

Once the switch is in the programming position, it may remain there as long as the operator wishes. The total programming cycle is set up to last only for 5ms and is controlled by one-shots as shown in the timing diagram, Fig. 2. The programmer timing follows the recommendation of the Signetics revised programming procedure and is easily adaptable to automatic programming and duplicating equipment.

#### CIRCUIT DESCRIPTION

Activating one of the four programming switches triggers one-shot No. 1 for 5 milliseconds. This activates gate No. 1 of the peripheral driver (75451) and, by releasing zener diode No. 1,  $V_{CC}$  is raised to 12.5V for 5 milliseconds while the 82S26 or 82S29 chip is disabled. (It should be mentioned that use of the 74121 eliminates contact bounce problems since it is non-retriggerable.)

After a time delay of 1 millisecond generated by one-shot No. 2, one-shot No. 3 is turned on. This turns off the output transistor of gate No. 2 of the 75451, enabling the programming current source. The constant current generator consists of LM309 No. 3 that is clamped to 22V by zener diode No. 2. The programming current is determined by the 59 ohm resistor and maintained at a constant 85mA.

An additional time delay of 1 millisecond, established by one-shot No. 4, guarantees that even slow current sources have reached the required current before the chip is enabled for 2ms to open the NiCr link. One-shot No. 5 establishes the chip enable ( $\overline{CE}$ ) signal and thus the programming time.

Figure 2 shows that  $V_{CC}$  for the memory is held at 12.5V for an additional 1 millisecond before the output of one-shot No. 1 allows the supply to return to 5V.

The two time delays of 1 millisecond generated by one-shots No. 2 and No. 4 can be shortened to the microsecond range for automatic programming equipment if fast switching and a fast current source, as the one discussed above, are chosen. Should it be desired to make the programmer self-contained, a power supply suggestion is also shown in Figure 2.





# SIGNETICS 1024-BIT PROGRAMMABLE ROM ■ 82S26/29

## ELECTRICAL CHARACTERISTICS $0^{\circ}\text{C} \leq T_A \leq 75^{\circ}\text{C}$ ; $4.75\text{V} \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
"0" Output Voltage			0.5	V	$I_{out} = 16\text{mA}$
"1" Output Leakage (82S26)			40	$\mu\text{A}$	$CE_1$ or $CE_2 = "1"$ , $V_{out} = 5.5\text{V}$
(82S29)			100	$\mu\text{A}$	$CE_1 = CE_2 = "0"$ , $V_{out} = 5.5\text{V}$
(82S29)	-40		+40	$\mu\text{A}$	$CE_1$ or $CE_2 = "1"$ , $V_{out} = .45$ to $2.4\text{V}$
"1" Output Current (82S29)	-2.0			mA	$CE_1 = CE_2 = "0"$ , $V_{out} = 2.4\text{V}$
"0" Input Current			-250	$\mu\text{A}$	$V_{in} = 0.45\text{V}$
"1" Input Current			50	$\mu\text{A}$	$V_{in} = 5.5\text{V}$
Input Threshold Voltage					
"0" Level	.85			V	
"1" Level			2.0	V	
Power Consumption (82S26)		105/525	130/685	mA/mW	
(82S29)		115/575	145/760	mA/mW	
Input Clamp Voltage	1.2			V	$I_{in} = -18\text{mA}$
Output Short Circuit Current	-20		-70	mA	$V_{out} = 0\text{Volts}$

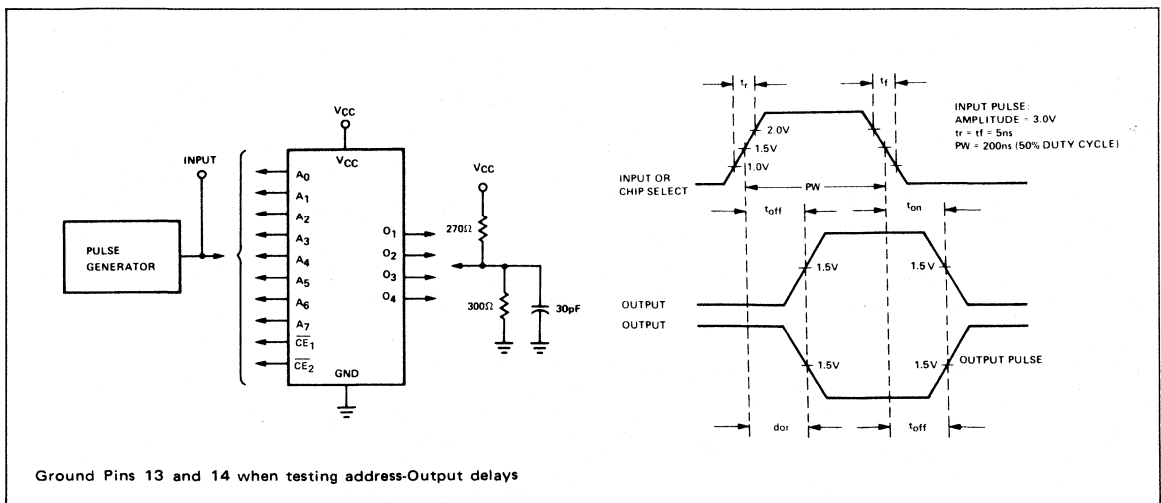
## SWITCHING CHARACTERISTICS $0 \leq T_A \leq 75^{\circ}\text{C}$ , $4.75 \leq V_{CC} \leq 5.25\text{V}$

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN.	TYP.	MAX.	UNITS	
Propagation Delay					
Address to Output			60	ns	$T_A = 25^{\circ}\text{C}$ only
			70	ns	
Chip Enable to Output			25	ns	$T_A = 25^{\circ}\text{C}$ only
			30	ns	

### NOTES

1. Positive current is defined as into the terminal referenced.
2. Manufacturer reserves the right to make design and process changes and improvements.

### AC TEST FIGURE AND WAVEFORM



## PRELIMINARY INFORMATION

## DIGITAL 54/74 TTL SERIES

### DESCRIPTION

The 10139 is an ECL 256-Bit Read Only Memory organized as 32 words with 8 bits per word. The words are selected by five binary address lines; full word decoding is incorporated on the chip. A chip enable input is provided for additional decoding flexibility, which causes all eight outputs to go to low state when the chip enable input is high. This device is fully compatible with all of Signetics series 10,000 products. Address to output access time is 15 ns typical. Power dissipation is 580 milliwatts typical with separate internal bond wires and metal systems for  $V_{CC1}$  and  $V_{CC2}$ . The 10139 may be programmed to any desired pattern by the user. The 10139 is suitable for use in high performance ECL systems. A Truth Table/Order Blank is attached.

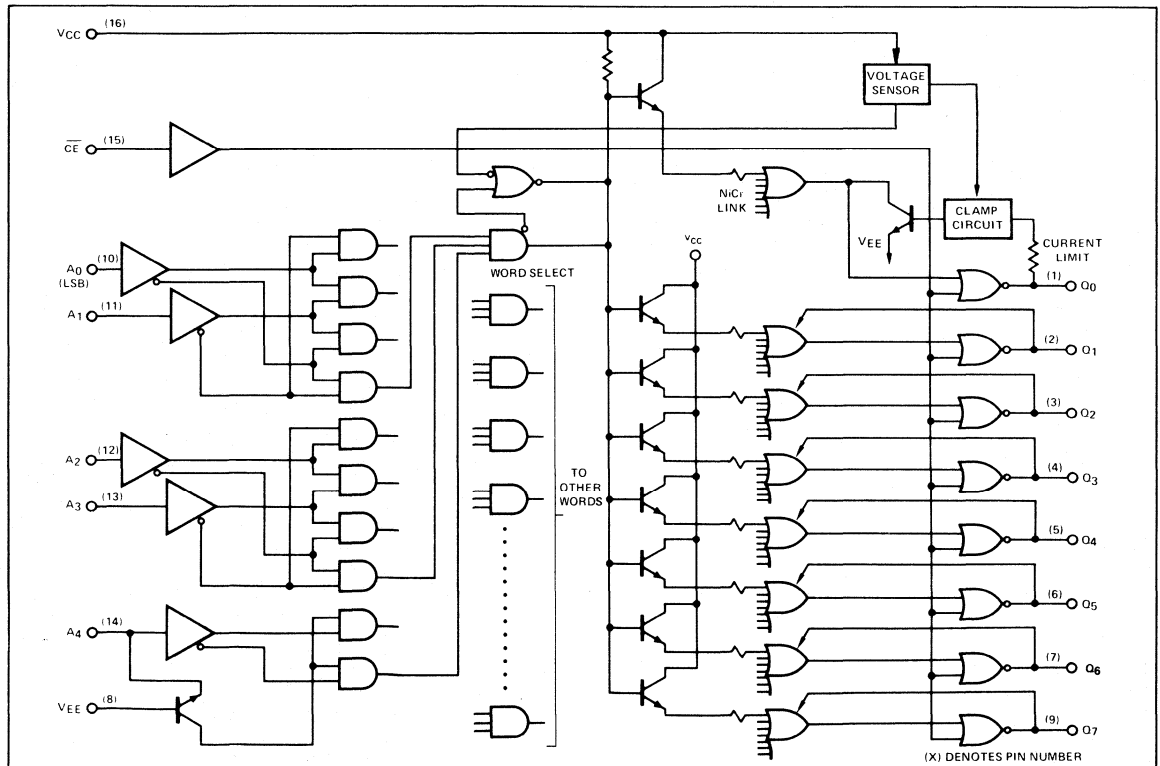
### TEMPERATURE RANGE

-30 to +85°C Operating Ambient

### RECOMMENDED OPERATING VOLTAGE

$V_{CC} = \text{GND}$ ,  $V_{EE} = -5.2\text{V} \pm 5\%$

### BLOCK DIAGRAM



### FEATURES

- 15 ns TYPICAL ACCESS TIME
- 16 PIN PACKAGE
- EASY PROGRAMMING
- FULLY DECODED
- FULLY COMPATIBLE WITH ECL 10,000 SERIES
- HIGH IMPEDANCE INPUTS 50K OHM PULLDOWN
- OPEN EMITTER OUTPUTS

### APPLICATIONS

PROGRAMMABLE LOGIC  
CONTROL STORES  
MICROPROGRAMMING  
VOLUME PRODUCTION  
HARDWIRED ALGORITHMS

### PACKAGE TYPE

F: 16 Pin CERDIP

**SIGNETICS ECL HIGH PERFORMANCE 256-PROM ■ 10139**
**PRELIMINARY ELECTRICAL CHARACTERISTICS** ( $T_A = +25^\circ\text{C}$ ,  $V_{CC} = 0\text{V}$ ,  $R_L = 50\Omega$ ,  $V_{EE} = -5.2\text{V}$ )

CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNIT
Power Supply Drain Current	$I_{EO}$		110	145	mAdc
Input Current $V_{IH} = -0.810\text{V}$ , $V_{IL} = -1.850\text{V}$	$I_{inH}$ $I_{inL}$	30		265	$\mu\text{Adc}$ $\mu\text{Adc}$
Output Voltage Logic "1" ( $V_{IH} = -0.810\text{V}$ , $V_{IL} = -1.850\text{V}$ )	$V_{OH}$	-0.960		-0.810	Vdc
Logic "0" ( $V_{IH} = -0.810\text{V}$ , $V_{ILA} = 1.850\text{V}$ )	$V_{OL}$	-1.990		-1.650	Vdc
Threshold Voltage Logic "1" ( $V_{IHA} = -1.105\text{V}$ , $V_{ILA} = -1.475\text{V}$ )	$V_{OHA}$	-0.980			Vdc
Logic "0" ( $V_{IHA} = -1.105\text{V}$ , $V_{ILA} = 1.475\text{V}$ )	$V_{OLA}$			-1.630	Vdc

**PRELIMINARY ELECTRICAL CHARACTERISTICS** ( $T_A = +25^\circ\text{C}$ ,  $V_{CC} = 0\text{V}$ ,  $V_{EE} = -5.2\text{V}$ ,  $R_L = 50\Omega$ )

CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNIT
Chip Enable Prop Delay			10	15	ns
Output Rise Time (20 to 80%)			4.2		ns
Output Fall Time (20 to 80%)			4.2		ns
Access Time Address to Output	$T_{AD}$		15	20	ns

## RECOMMENDED PROGRAMMING PROCEDURE

The 10139 is shipped with all bits at logical "0" (low). To write logical "1's", proceed as follows:

### MANUAL (see Fig. 1)

#### STEP 1

Connect  $V_{EE}$  (Pin 8) to ground and  $V_{CC}$  (Pin 16) to +5.2 volts. Address the word to be programmed by applying 4.0 to 4.6 volts for a logic "1" and 0.0 to 1.0 volts for a logic "0" to the appropriate address inputs.

#### STEP 2

Raise  $V_{CC}$  (Pin 16) to 12 volts.

#### STEP 3

After  $V_{CC}$  has stabilized at 12 volts (including any ringing which may be present on the  $V_{CC}$  line) apply a current pulse of 2.5 mA to the output pin corresponding to the bit to be programmed to a logic "1".

#### STEP 4

Return  $V_{CC}$  to 5.2 volts.

CAUTION: To prevent excessive chip temperature rise,  $V_{CC}$  should not be allowed to remain at 12 volts for more than 1 second.

#### STEP 5

Verify that the selected bit has programmed by connecting a 460 $\Omega$  resistor to ground and measuring the voltage at the output pin. If a logic "1" is not detected at the output, the procedure should be repeated once.

## PROGRAMMING SPECIFICATIONS

CHARACTERISTIC	SYMBOL	LIMITS			UNITS	CONDITIONS
		MIN.	TYP.	MAX.		
Power Supply Voltage To Program To Verify	$V_{CCP}$ $V_{CCV}$	11.5	12.0	12.5	Volts	
		5.0	5.2	5.4	Volts	
Programming Supply Current	$I_{CCP}$			250	mA	$V_{CC} = 12.0$ Volts
Address Voltage logical "1" logical "0"	$V_{IH}$ $V_{IL}$	4.0		4.6	Volts	
		0.0		1.0	Volts	
Max. Time at $V_{CC} = V_{CCP}$				1.0	Sec.	
Output Programming Current	$I_{OP}$	2.0	2.5	3.0	mA	
Output Program Pulse Width	$t_p$	0.5		1.0	ms	
Output Pulse Rise Time				10	$\mu$ s	
Programming Pulse Delay (1) following $V_{CC}$ change between output pulses	$t_d$ $t_{d1}$	0.1		1.0	ms	
		0.01		1.0	ms	

#### NOTE:

(1) Maximum is specified to minimize the amount of time  $V_{CC}$  is at 12 volts.

#### STEP 6

If verification is positive, proceed to the next bit to be programmed.

### AUTOMATIC (see Fig. 2)

#### STEP 1

Connect  $V_{EE}$  (Pin 8) to ground and  $V_{CC}$  (Pin 16) to +5.2 volts. Apply the proper address data and raise  $V_{CC}$  (Pin 16) to 12 volts.

#### STEP 2

After a minimum delay of 100  $\mu$ s and a maximum delay of 1.0 ms, apply a 2.5 mA current pulse to the first bit to be programmed ( $0.5 \leq PW \leq 1$  ms).

#### STEP 3

Repeat Step 2 for each bit of the selected word specified as a logic "1". (Program only one bit at a time; The delay between output programming pulses should be equal to or less than 1.0 ms.)

#### STEP 4

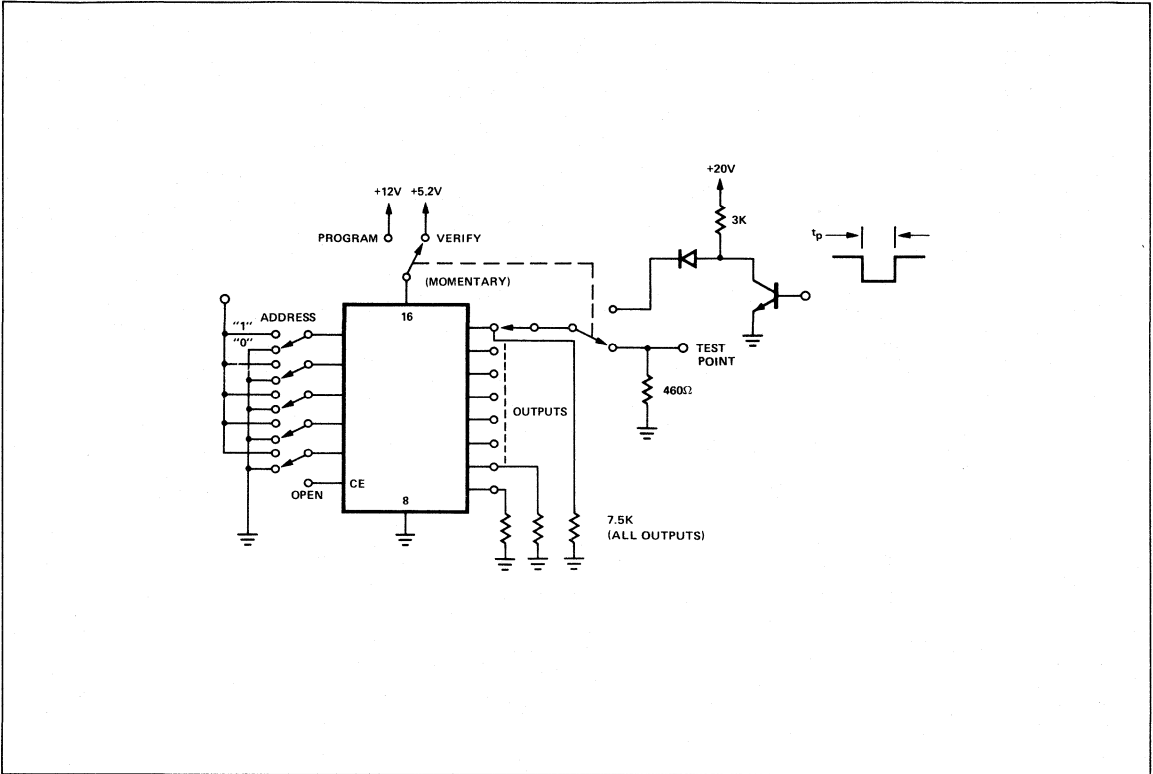
After all the desired bits of the selected word have been programmed, change address data and repeat Steps 2 and 3.

NOTE: If all the maximum times listed above are maintained, the entire memory will program in less than 1 second. Therefore, it would be permissible for  $V_{CC}$  to remain at 12 volts during the entire programming time.

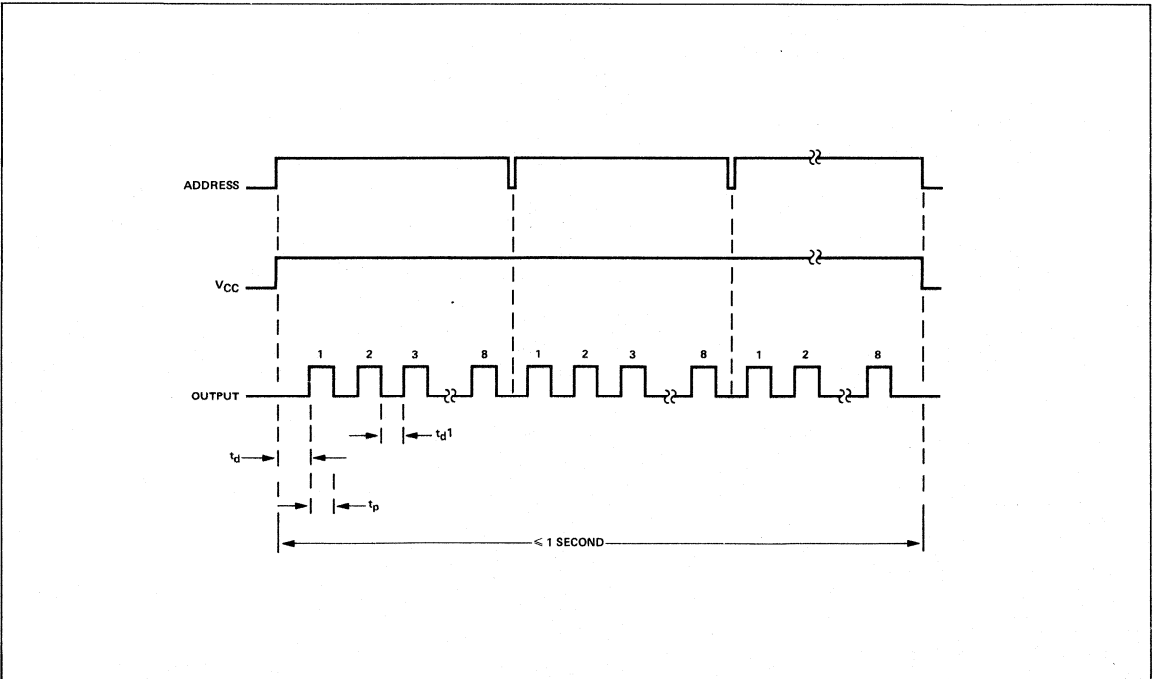
#### STEP 5

After stepping through all address words, return  $V_{CC}$  to +5.2 and verify that each bit has programmed. If one or more bits have not programmed, repeat the entire procedure once.

MANUAL PROGRAMMING CIRCUIT



AUTOMATIC PROGRAMMING CIRCUIT



## DESCRIPTION

The 10140, 10148 and 10151 are 64 Bit ECL Random Access Memories (RAM's) organized as 64 words with 1 bit per word. The words are selected by six binary address lines; full word decoding is incorporated on the chip. Two chip enable input lines are provided for additional decoding flexibility. The chip is disabled when either chip enables are high, which causes the output of the 10140 and 10148 to go low.

The 10151 has an internal latch on the chip to provide the Write-While-Read capability. When the latch control line,  $\bar{L}$  is a "1" and data is being read from the 10151 the latch is effectively bypassed. The data at the output will be that of the addressed word. When  $\bar{L}$  goes from a logic "1" to logic "0" the outputs are latched and will remain latched regardless of the state of any other address or control line. When  $\bar{L}$  goes from "0" to "1" the outputs unlatch and will take the state of the addressed word. The 10151 and 10148 logic levels are fully compatible with the 10,000 series and are specified for driving a 50Ω load. The 10140 is compatible with series 10,000 ECL except the output is specified for driving a 90Ω load.

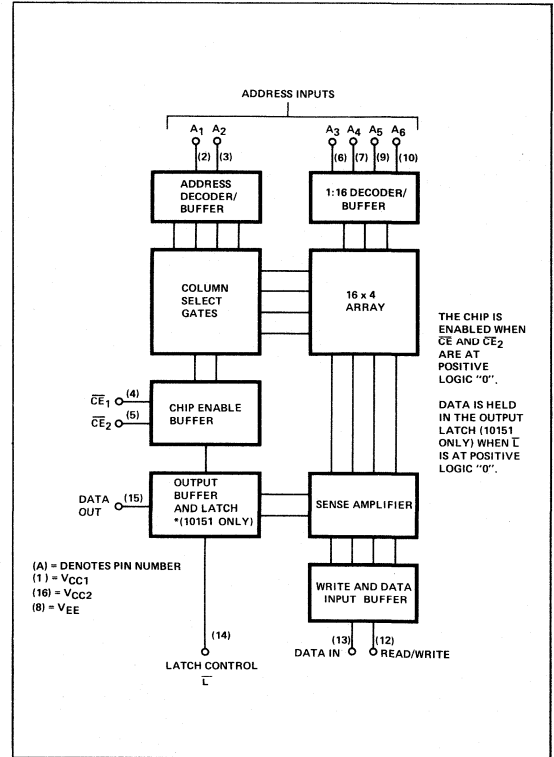
## FEATURES

- 10 ns TYPICAL ACCESS TIME
- 16 PIN PACKAGE
- ON THE CHIP LATCH (AVAILABLE ON 10151)
- ON THE CHIP DECODING
- TWO CHIP ENABLE CONTROL LINES
- HIGH IMPEDANCE INPUTS 50k OHM PULL-DOWN
- OPEN EMITTER OUTPUTS

## APPLICATIONS

SCRATCH PAD MEMORY  
 BUFFER MEMORY  
 ACCUMULATOR REGISTER  
 CONTROL STORE

## LOGIC DIAGRAM



## TRUTH TABLE (10151)

$\bar{CE}$	$\bar{RW}$	$\bar{L}$	MODE	OUTPUTS
0	0	0	Write Data	
0	0	1	Write Data	
0	1	0	Read	Data stored in addressed word
0	1	1	Read	Data stored in addressed word
1	0	0	Chip Disabled	Data from last address when $\bar{CE} = "0"$
1	0	1	Chip Disabled	Logical "1"
1	1	0	Chip Disabled	Data from last address when $\bar{CE} = "0"$
1	1	1	Chip Disabled	Logical "1"

**ABSOLUTE MAXIMUM RATINGS**

CHARACTERISTIC	SYMBOL	RATING	UNIT
Power Supply Voltage ( $V_{CC} = 0$ )	$V_{EE}$	-8	Vdc
Input Voltage ( $V_{CC} = 0$ )	$V_{in}$	0 to $V_{IL}$ min	Vdc
Output Source Current	$I_o$	40	mAdc
Storage Temperature Range	$T_{stg}$	-55 to +125	°C
Operating Junction Temperature	$T_J$	110	°C
Operating Temperature Range	$T_A$	-30 to +85	°C
Power Supply Regulation Required	—	±10% ±5%	—

$V_{CC1} = V_{CC2} = \text{Gnd}$

**SWITCHING CHARACTERISTICS**  $T_A = 25^\circ\text{C}$ ,  $R_L = 50\Omega$  for 10148 and 10151,  $R_L = 90\Omega$  for 10140

CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNIT
Chip Enable Turn-On	$t_{CE-D+}$	—	8	12	ns
Access Time for Address to Output	$t_{A+D+}$	—	10	15	ns
	$t_{A+D-}$	—	10	15	
	$t_{A-D+}$	—	10	15	
	$t_{A-D-}$	—	10	15	
Write Pulse Width	$t_w(R/W)$	10			ns
Chip Enable Pulse Width	$t_w(CE)$	13			ns
Set-Up Time for Data to Write	$t_{set}(D\pm R/W+)$	10			ns
Set-Up Time for Data to Chip Enable	$t_{set}(D\pm CE+)$	10			ns
Set-Up Time for Write to Chip Enable	$t_{set}(W-CE+)$	10			ns
Set-Up Time for Chip Enable to Write	$t_{set}(CE-R/W+)$	13			ns
Set-Up Time for Data to Latch (10151 only)	$t_{set}(D\pm I-)$				ns
Set-Up Time for Latch Release to Data (10151 only)	$t_{set}(I+D\pm)$				ns
Set-Up Time for Latch to Address (10151 only)	$t_{set}(I-A\pm)$				ns

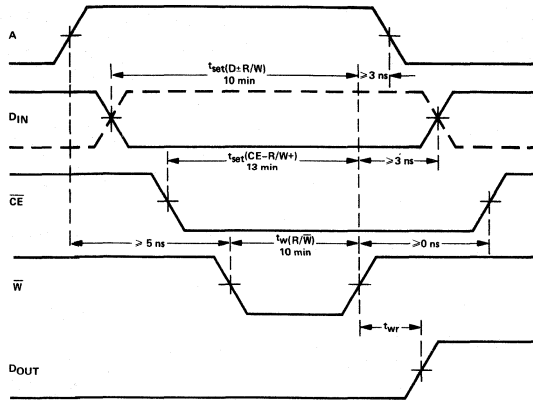
**ELECTRICAL CHARACTERISTICS**  $T_A = 25^\circ\text{C}$ ,  $R_L = 50\Omega$  for 10148 and 10151,  $R_L = 90\Omega$  for 10140

CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNIT
Power Supply Drain Current ( $V_{EE} = -5.2\text{ V}$ )	$I_{EO}$	—	80	—	mAdc
Input Current ( $V_{IH} = -0.810\text{ V}$ , $V_{EE} = -5.2\text{ V}$ ) ( $V_{IL} = -1.850\text{ V}$ , $V_{EE} = -5.2\text{ V}$ )	$I_{inH}$	—	—	265	$\mu\text{Adc}$
	$I_{inL}$	0.5	—	—	
Output Voltage Logic "1" ( $V_{IH} = -0.810\text{ V}$ , $V_{IL} = -1.850\text{ V}$ , $V_{EE} = -5.2\text{ V}$ ) Logic "0" ( $V_{IH} = -0.810\text{ V}$ , $V_{IL} = -1.850\text{ V}$ , $V_{EE} = -5.2\text{ V}$ )	$V_{OH}$	-0.960	—	-0.810	Vdc
	$V_{OL}$	-1.990	—	-1.650	Vdc
Threshold Voltage Logic "1" ( $V_{IHA} = -1.105\text{ V}$ , $V_{ILA} = -1.475\text{ V}$ , $V_{EE} = -5.2\text{ V}$ ) Logic "0" ( $V_{IHA} = -1.105\text{ V}$ , $V_{ILA} = -1.475\text{ V}$ , $V_{EE} = -5.2\text{ V}$ )	$V_{QHA}$	-0.980	—	—	Vdc
	$V_{OLA}$	—	—	-1.630	Vdc

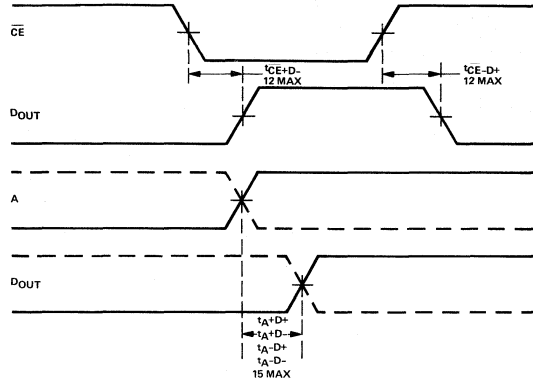


TIMING DIAGRAMS

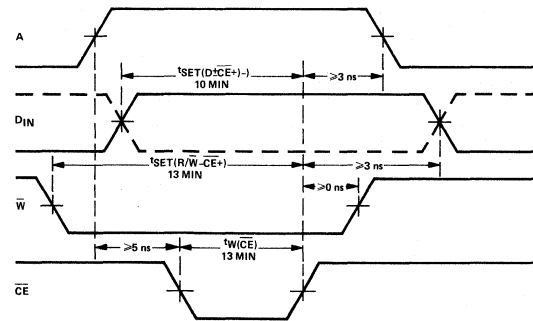
WRITE TIMING DIAGRAMS—WRITE STROBE MODE



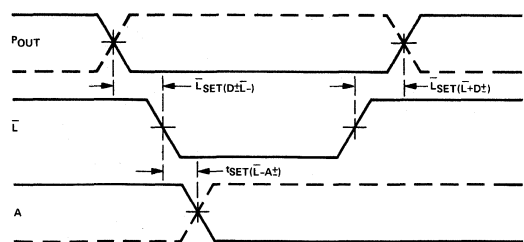
READ TIMING DIAGRAM



CHIP ENABLE STROBE MODE



10151 LATCH TIMING DIAGRAM



10145 F, I -30°C to +85°C  
DIGITAL 10,000 ECL SERIES

## DESCRIPTION

The 10145 is an ECL 64-bit read-write random access memory organized as 16 words of 4 bits each. Words are selected through fully decoded and buffered inputs when the chip enable ( $\overline{CE}$ ) is low. Data is written into the selected word by bringing the READ/WRITE input low. Outputs are low during write.

On-chip input pulldown resistors allow any unused inputs to be left open. Open emitter outputs allow corresponding bits of different devices to be tied together to form a "Wire OR" logic connection.

The 10145 utilizes separate internal metal systems and wire bonds for  $V_{CC1}$  and  $V_{CC2}$ . The exceptionally high speed of the 10145 makes it particularly suited for register file and and scratch pad applications.

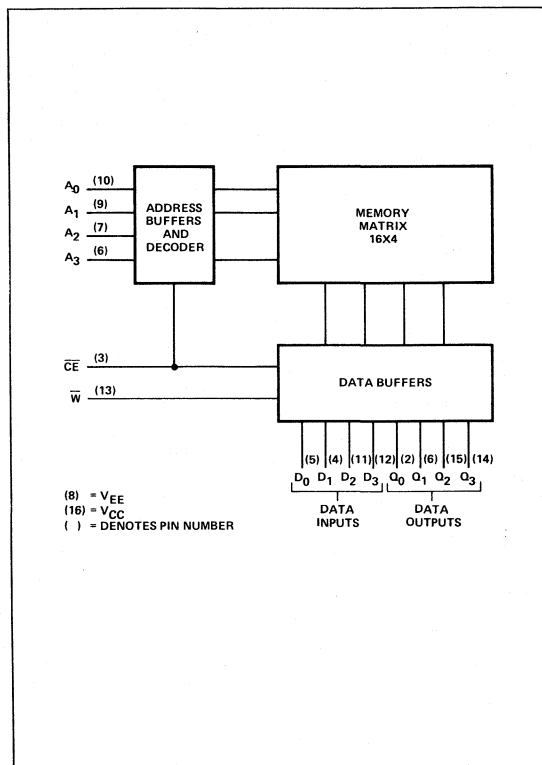
## FEATURES

- 8.5ns ADDRESS ACCESS TIME (TYP)
- INPUT PULLDOWN RESISTORS
- OPEN EMITTER OUTPUTS AND CHIP ENABLE INPUT FOR MEMORY EXPANSION
- 50 Ohm OUTPUT SPECIFICATION
- SINGLE -5.2V POWER SUPPLY
- FULLY DECODED INPUTS
- FULLY COMPATIBLE WITH SIGNETICS 10,000 SERIES FAMILY OF INTEGRATED CIRCUITS

## APPLICATIONS

SCRATCH PAD MEMORIES  
BUFFER MEMORIES  
REGISTER FILES  
CONTROL STORES

## BLOCK DIAGRAM



## PACKAGE TYPES

F: 16 Pin Cerdip  
I: 16 Pin Laminated Ceramic

## ELECTRICAL CHARACTERISTICS $V_{EE} = -5.2V, V_{CC} = 0V, R_L = 50\Omega$ TO $-2.0V$

CHARACTERISTIC	SYMBOL	CONDITIONS	TEMP.	MIN.	TYP.	MAX.	UNITS
Supply Current	$I_E$		25°C		116	145	mA
Input Current (Pins 3, 6, 7, 9, 10)	$I_{INH}$	$V_{IN} = V_{IH} \text{ MAX.}$	25°C			200	$\mu A$
Input Current (Pins 4, 5, 11, 12)	$I_{INH}$	$V_{IN} = V_{IH} \text{ MAX.}$	25°C			220	$\mu A$
Input Current (Pin 13)	$I_{INH}$	$V_{IN} = V_{IH} \text{ MAX.}$	25°C			455	$\mu A$
Input Current (All Inputs)	$I_{INL}$	$V_{IN} = V_{IL} \text{ MIN.}$	25°C	0.5			$\mu A$

## ELECTRICAL CHARACTERISTICS (Cont'd)

CHARACTERISTIC	SYMBOL	CONDITIONS	TEMP.	MIN.	TYP.	MAX.	UNITS
Output Voltage	$V_{OH}$	$V_{IN} = V_{IH} \text{ MAX.},$ $V_{IL} \text{ MIN.}$	-30°C 25°C 85°C	-1.06 -0.96 -0.89		-0.89 -0.81 -0.70	Vdc
Output Voltage	$V_{OL}$	$V_{IN} = V_{IH} \text{ MAX.},$ $V_{IL} \text{ MIN.}$	-30°C 25°C 85°C	-1.89 -1.85 -1.825		-1.675 -1.65 -1.615	Vdc
Output Voltage (Threshold)	$V_{OHA}$	$V_{IN} = V_{IHA}, V_{ILA}$	-30°C 25°C 85°C	-1.08 -0.98 -0.91			Vdc
Output Voltage (Threshold)	$V_{OLA}$	$V_{IN} = V_{IHA}, V_{ILA}$	-30°C 25°C 85°C			-1.655 -1.63 -1.595	Vdc

SWITCHING CHARACTERISTICS  $V_{EE} = -3.2V, V_{CC} = 2V, R_L = 50\Omega \text{ TO GND}$ 

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNITS
Access Time – Chip Enable to Output	$t_{\overline{CE}} - Q+, t_{\overline{CE}} + Q-$		5.0		ns
Address to Output	$t_A + Q+, t_A - Q+$ $t_A + Q-, t_A - Q-$		8.5		ns
Write Strobe Mode					
Data Set-up	$t_{SET}(D \pm R/\overline{W}+)$		7.5		ns
Chip Enable Set-up	$t_{SET}(\overline{CE} - R/\overline{W}+)$		11.0		ns
Address	$t_{SET}(A \pm R/\overline{W}-)$		3.5		ns
Data Hold	$t_{HOLD}(D \mp R/\overline{W}+)$		3.0		ns
Chip Enable Hold	$t_{HOLD}(\overline{CE} + R/\overline{W}+)$		3.0		ns
Address Hold	$t_{HOLD}(A \mp R/\overline{W}+)$		3.5		ns
Recovery Time	$t_{R/\overline{W}+} Q+, t_{R/\overline{W}+} Q-$		7.5		ns
Write Pulse Width	$t_W(R/\overline{W})$		7.5		ns
Chip Enable Strobe Mode					
Data Set-up	$t_{SET}(D \pm \overline{CE}+)$		7.5		ns
Read/Write Set-up	$t_{SET}(R/\overline{W} - \overline{CE}+)$		11.0		ns
Address Set-up	$t_{SET}(A \pm \overline{CE}-)$		3.0		ns
Data Hold	$t_{HOLD}(D \mp \overline{CE}+)$		3.0		ns
Read/Write Hold	$t_{HOLD}(R/\overline{W} + \overline{CE}+)$		3.0		ns
Address Hold	$t_{HOLD}(A \mp \overline{CE}+)$		3.0		ns
Chip Enable Pulse Width	$t_W(\overline{CE})$		7.5		ns
Rise Time (20%-80%)	$t_r$		2.5		ns
Fall Time (20%-80%)	$t_f$		2.5		ns

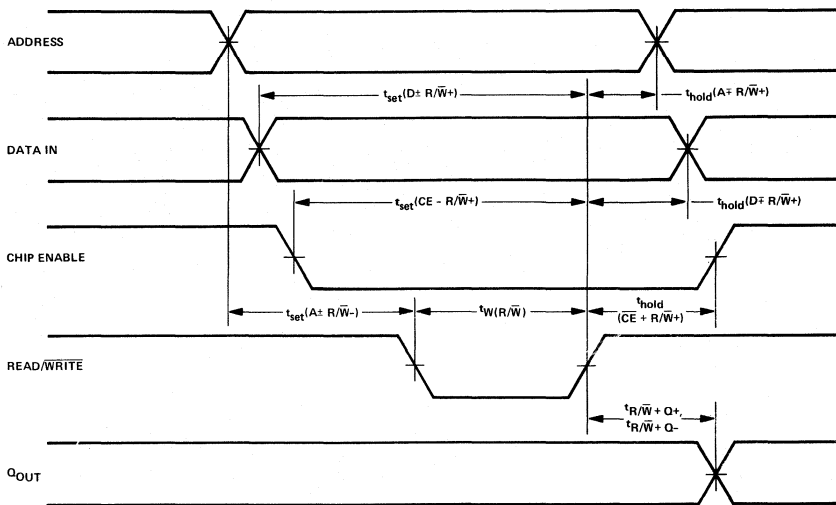
## TEST VOLTAGE VALUES

Vdc ± 1%

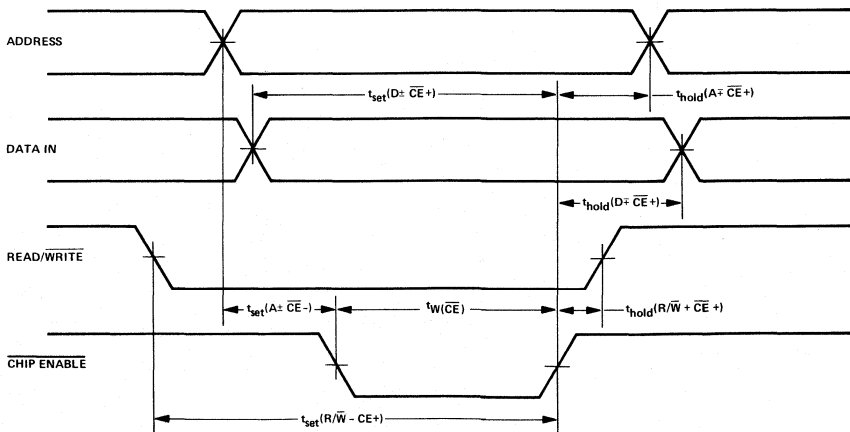
@ Test Temperature	$V_{IH} \text{ max}$	$V_{IL} \text{ min}$	$V_{IHA} \text{ min}$	$V_{ILA} \text{ max}$	$V_{EE}$
-30°C	-0.890	-1.890	-1.205	-1.500	-5.2
+25°C	-0.810	-1.850	-1.105	-1.475	-5.2
+85°C	-0.700	-1.825	-1.035	-1.440	-5.2

TIMING DIAGRAMS

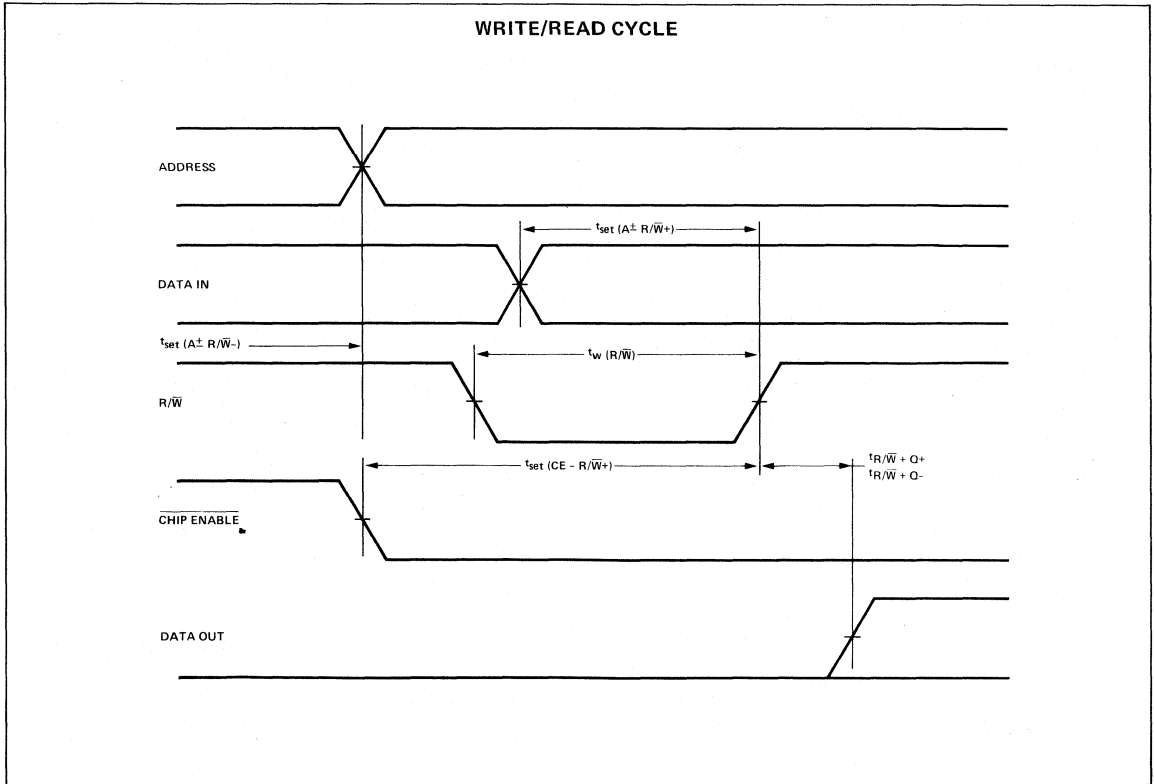
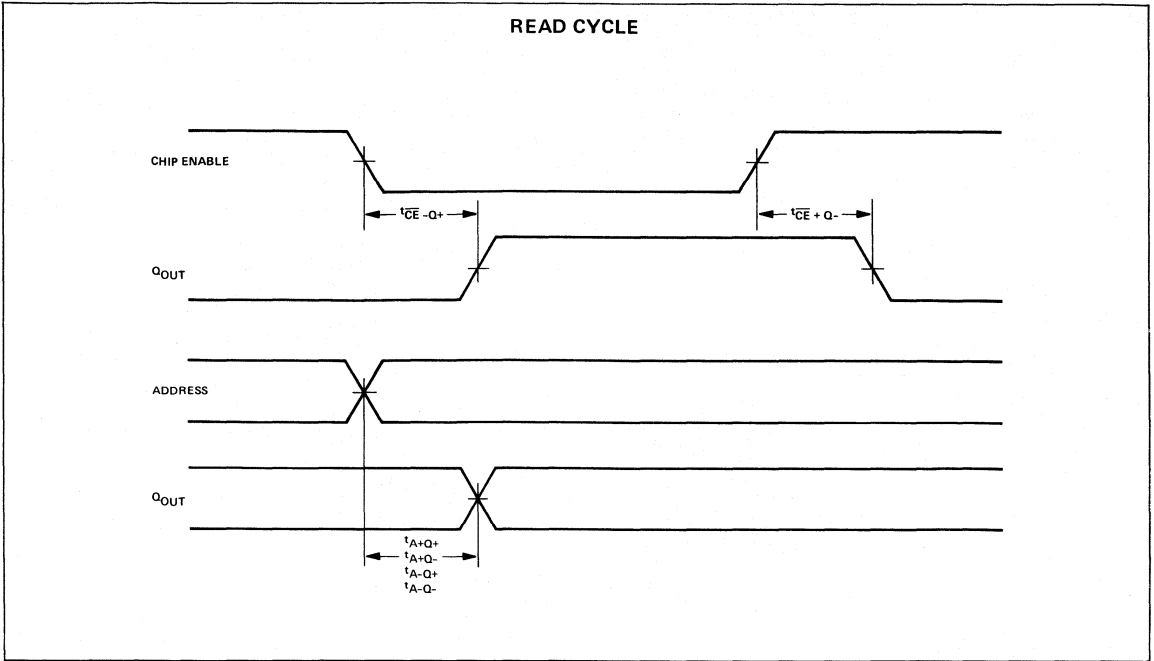
WRITE CYCLE  
READ/WRITE STROBE MODE



WRITE CYCLE  
CHIP ENABLE STROBE MODE



TIMING DIAGRAMS (Cont'd)



# CUSTOMER ORDERING INFORMATION

N8205 - CB175 ASCII-TO-EBCDIC, EBCDIC-TO-ASCII  
 N8204 - CB504 ASCII-TO-EBCDIC CODE CONVERTER  
 N8204 - CB505 EBCDIC-TO-ASCII CODE CONVERTER

## ASCII (ADDRESS) TO EBCDIC (DATA) 8205 — CB175 FIRST HALF 8204 — CB504

0	00000000	1	00000001	2	00000010	3	00000011	128	00100000	129	00100001	130	00100010	131	00100011
4	00110111	5	00101101	6	00101110	7	00101111	132	00100100	133	00010101	134	00000110	135	00010111
8	00010110	9	00000101	10	00100101	11	00000111	136	00101000	137	00101001	138	00101010	139	00101011
12	00001100	13	00001101	14	00001110	15	00001111	140	00101100	141	00001001	142	00001010	143	00010111
16	00010000	17	00010001	18	00010010	19	00010011	144	00110000	145	00110001	146	00011010	147	00110011
20	00111100	21	00111101	22	00110010	23	00100110	148	00110100	149	00110101	150	00110110	151	00001000
24	00011000	25	00011001	26	00111111	27	00100111	152	00111000	153	00111001	154	00111010	155	00111011
28	00011100	29	00011101	30	00011110	31	00011111	156	00000100	157	00001000	158	00111110	159	11100001
32	01000000	33	01001111	34	01111111	35	01111111	160	01000001	161	01000010	162	01000011	163	01000010
36	01011011	37	01101100	38	01010000	39	01111101	164	01000101	165	01000110	166	01000111	167	01001000
40	01001101	41	01101101	42	01011100	43	01001110	168	01001001	169	01010001	170	01010010	171	01010011
44	01101011	45	01100000	46	01001011	47	01100001	172	01010100	173	01010101	174	01010110	175	01010111
48	11110000	49	11110001	50	11110010	51	11110011	176	01011000	177	01011001	178	01100010	179	01100011
52	11110100	53	11110101	54	11110110	55	11110111	180	01100100	181	01100101	182	01100110	183	01100111
56	11111000	57	11111001	58	01111010	59	01011110	184	01101000	185	01101001	186	01110000	187	01110001
60	01001100	61	01111110	62	01101110	63	01101111	188	01110010	189	01110011	190	01110100	191	01110101
64	01111100	65	11000001	66	11000010	67	11000011	192	01110110	193	01110111	194	01111000	195	10000000
68	11000100	69	11000101	70	11000110	71	11000111	196	10001010	197	10001011	198	10001100	199	10001101
72	11001000	73	11001001	74	11010001	75	11010010	200	10001110	201	10001111	202	10001000	203	10011010
76	11010011	77	11010100	78	11010101	79	11010110	204	10011011	205	10011100	206	10011101	207	10011110
80	11010111	81	11011000	82	11011001	83	11100010	208	10011111	209	10100000	210	10101010	211	10101011
84	11100011	85	11100100	86	11100101	87	11100110	212	10101010	213	10101101	214	10101110	215	10101111
88	11100111	89	11110000	90	11110001	91	01001010	216	10110000	217	10110001	218	10110010	219	10110011
92	11100000	93	01010101	94	01011111	95	01101101	220	10110100	221	10110101	222	10110110	223	10110111
96	01111001	97	10000001	98	10000010	99	10000011	224	10111000	225	10111001	226	10111010	227	10111011
100	10000100	101	10000101	102	10000110	103	10000111	228	10111100	229	10111101	230	10111110	231	10111111
104	10001000	105	10001001	106	10010001	107	10010010	232	11001010	233	11001011	234	11001100	235	11001101
108	10010011	109	10010100	110	10010101	111	10010110	236	11001110	237	11001111	238	11011010	239	11011011
112	10010111	113	10011000	114	10011001	115	10100010	240	11011100	241	11011101	242	11011110	243	11011111
116	10100011	117	10100100	118	10100101	119	10100110	244	11101010	245	11101011	246	11101100	247	11101101
120	10100111	121	10101000	122	10101001	123	11000000	248	11101110	249	11101111	250	11111010	251	11111011
124	01101010	125	11010000	126	10100001	127	00000111	252	11111100	253	11111101	254	11111110	255	11111111

## EBCDIC (ADDRESS) TO ASCII (DATA) 8205 — CB175 SECOND HALF 8204 — CB505

256	00000000	257	00000001	258	00000010	259	00000011	384	11000011	385	01100001	386	01100010	387	01100011
260	00011100	261	00001001	262	00001010	263	01111111	388	01100100	389	01100101	390	01100110	391	01100111
264	00010111	265	10001101	266	10001110	267	00001011	392	01101000	393	01101001	394	11001000	395	11001001
268	00001100	269	00001101	270	00001110	271	00001111	396	11000110	397	11000111	398	11001000	399	11001001
272	00010000	273	00010001	274	00010010	275	00010011	400	11001010	401	11001011	402	01101011	403	01101100
276	00111101	277	10000101	278	00001000	279	10000111	404	01101101	405	01101110	406	01101111	407	01110000
280	00011000	281	00011001	282	10010010	283	10001111	408	01110001	409	01110010	410	11001011	411	11001100
284	00011100	285	00011101	286	00011110	287	00011111	412	11001101	413	11001110	414	11001111	415	11010000
288	10000000	289	10000001	290	10000010	291	10000011	416	11010001	417	01111110	418	01110011	419	01110100
292	10000100	293	00001010	294	00001011	295	00010101	420	01110101	421	01110110	422	01110111	423	01111000
296	10001000	297	10001001	298	10001010	299	10001011	424	01111001	425	01111010	426	11010010	427	11010011
300	10001100	301	00000101	302	00000110	303	00000111	428	11010100	429	11010101	430	11010110	431	11010111
304	10010000	305	10010001	306	00010110	307	10010011	432	11011000	433	11011001	434	11011010	435	11011011
308	10010100	309	10010101	310	10010110	311	00000100	436	11011100	437	11011101	438	11011110	439	11011111
312	10011000	313	10011001	314	10011010	315	10011011	440	11100000	441	11100001	442	11100010	443	11100011
316	00010100	317	00010101	318	10011110	319	00011010	444	11100100	445	11100101	446	11100110	447	11100111
320	00100000	321	01000000	322	01000001	323	10100010	448	01111011	449	01000001	450	01000010	451	01000011
324	01000011	325	01001000	326	01001001	327	01001010	452	01000100	453	01000101	454	01000110	455	01000111
328	10100111	329	10101000	330	01011011	331	01011110	456	01001000	457	01001001	458	11101000	459	11101001
332	00111100	333	00101000	334	00101011	335	00100001	460	11101010	461	11101011	462	11101100	463	11101101
336	00100110	337	10101001	338	10101010	339	10101011	464	01111101	465	01001010	466	01001011	467	01001100
340	10101100	341	10101101	342	10101110	343	10101111	468	01001101	469	01001110	470	01001111	471	01010000
344	01101000	345	01101001	346	01101101	347	00100100	472	01010001	473	01010010	474	11101110	475	11101111
348	00101010	349	00101001	350	00111011	351	01111110	476	11100000	477	11100001	478	11100010	479	11100011
352	00101101	353	00101111	354	10110010	355	10110011	480	01011100	481	10011111	482	01010011	483	01010100
356	01101010	357	10110101	358	10110110	359	10110111	484	01010101	485	01010110	486	01010111	487	01011000
360	10111000	361	10111001	362	01111100	363	00101100	488	01011001	489	01011010	490	11110100	491	11110101
364	00100101	365	01011111	366	00011110	367	00111111	492	11110110	493	11110111	494	11111000	495	11111001
368	10111010	369	10111011	370	10111100	371	10111101	496	00110000	497	00110001	498	00110010	499	00110011
372	10111110	373	10111111	374	11000000	375	11000001	500	00101000	501	00110101	502	00110110	503	00110111
376	11000010	377	01100000	378	00111010	379	00100011	504	00111000	505	00111001	506	11111010	507	11111011
380	01000000	381	00100111	382	00111101	383	00100010	508	11111100	509	11111101	510	11111110	511	11111111

N82281 – CB 162 PATTERN  
 USASC II ROW CHARACTER GENERATOR

		0		0		0		0		1		1		1		1	
		0		1		0		1		0		1		0		1	
		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>		0 <sub>4</sub> 0 <sub>3</sub> 0 <sub>2</sub> 0 <sub>1</sub>	
A <sub>0</sub> A <sub>1</sub> A <sub>2</sub> A <sub>3</sub> A <sub>4</sub> A <sub>5</sub> A <sub>6</sub> A <sub>7</sub> A <sub>8</sub>	A <sub>9</sub>	0 1		0 1		0 1		0 1		0 1		0 1		0 1		0 1	
0 0 0	000 001 010 011 100 101 110 111	O		A		B		C		D		E		F		G	
0 0 1	000 001 010 011 100 101 110 111	H		I		J		K		L		M		N		O	
0 1 0	000 001 010 011 100 101 110 111	P		Q		R		S		T		U		V		W	
0 1 1	000 001 010 011 100 101 110 111	X		Y		Z		[		\		]		^		_	
1 0 0	000 001 010 011 100 101 110 111	`		a		b		c		d		e		f		g	
1 0 1	000 001 010 011 100 101 110 111	h		i		j		k		l		m		n		o	
1 1 0	000 001 010 011 100 101 110 111	p		q		r		s		t		u		v		w	
1 1 1	000 001 010 011 100 101 110 111	x		y		z		{				~		?			













25	89	153	217
26	90	154	218
27	91	155	219
28	92	156	220
29	93	157	221
30	94	158	222
31	95	159	223
32	96	160	224
33	97	161	225
34	98	162	226
35	99	163	227
36	100	164	228
37	101	165	229
38	102	166	230
39	103	167	231
40	104	168	232
41	105	169	233
42	106	170	234
43	107	171	235
44	108	172	236
45	109	173	237
46	110	174	238
47	111	175	239
48	112	176	240
49	113	177	241
50	114	178	242
51	115	179	243
52	116	180	244
53	117	181	245
54	118	182	246
55	119	183	247
56	120	184	248
57	121	185	249
58	122	186	250
59	123	187	251
60	124	188	252
61	125	189	253
62	126	190	254
63	127	191	255





(8223,8224) (82S23, 82S123) (10139)

CB (XXX) 256 BIT READ ONLY MEMORIES TRUTH TABLE/ORDER BLANK

CUSTOMER: \_\_\_\_\_  
P.O. NO.: \_\_\_\_\_  
YOUR PART NO.: \_\_\_\_\_  
DATE: \_\_\_\_\_

THIS PORTION TO BE COMPLETED BY SIGNETICS  
PART NO.: \_\_\_\_\_  
S.D. NO.: \_\_\_\_\_  
DATE RECEIVED: \_\_\_\_\_

WORD	INPUTS						OUTPUTS							
	A <sub>4</sub>	A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	ENABLE	B <sub>7</sub>	B <sub>6</sub>	B <sub>5</sub>	B <sub>4</sub>	B <sub>3</sub>	B <sub>2</sub>	B <sub>1</sub>	B <sub>0</sub>
0	0	0	0	0	0	0								
1	0	0	0	0	1	0								
2	0	0	0	1	0	0								
3	0	0	0	1	1	0								
4	0	0	1	0	0	0								
5	0	0	1	0	1	0								
6	0	0	1	1	0	0								
7	0	0	1	1	1	0								
8	0	1	0	0	0	0								
9	0	1	0	0	1	0								
10	0	1	0	1	0	0								
11	0	1	0	1	1	0								
12	0	1	1	0	0	0								
13	0	1	1	0	1	0								
14	0	1	1	1	0	0								
15	0	1	1	1	1	0								
16	1	0	0	0	0	0								
17	1	0	0	0	1	0								
18	1	0	0	1	0	0								
19	1	0	0	1	1	0								
20	1	0	1	0	0	0								
21	1	0	1	0	1	0								
22	1	0	1	1	0	0								
23	1	0	1	1	1	0								
24	1	1	0	0	0	0								
25	1	1	0	0	1	0								
26	1	1	0	1	0	0								
27	1	1	0	1	1	0								
28	1	1	1	0	0	0								
29	1	1	1	0	1	0								
30	1	1	1	1	0	0								
31	1	1	1	1	1	0								
ALL	X	X	X	X	X	1	1	1	1	1	1	1	1	1

(82S26) (82S29)  
 CB (XXXX) 1024 BIT READ ONLY MEMORY TRUTH TABLE/ORDER BLANK

CUSTOMER: \_\_\_\_\_ THIS PORTION TO BE COMPLETED BY SIGNETICS

P.O. NO.: \_\_\_\_\_ PART NO.: \_\_\_\_\_

YOUR PART NO.: \_\_\_\_\_ S.D. NO.: \_\_\_\_\_

DATE: \_\_\_\_\_ DATE RECEIVED: \_\_\_\_\_

Word	OUTPUT				Word	OUTPUT				Word	OUTPUT				Word	OUTPUT			
	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>
0					64					128					192				
1					65					129					193				
2					66					130					194				
3					67					131					195				
4					68					132					196				
5					69					133					197				
6					70					134					198				
7					71					135					199				
8					72					136					200				
9					73					137					201				
10					74					138					202				
11					75					139					203				
12					76					140					204				
13					77					141					205				
14					78					142					206				
15					79					143					207				
16					80					144					208				
17					81					145					209				
18					82					146					210				
19					83					147					211				
20					84					148					212				
21					85					149					213				
22					86					150					214				
23					87					151					215				
24					88					152					216				
25					89					153					217				





(8228)  
4096 BIT READ ONLY MEMORY TRUTH TABLE/ORDER BLANK

CUSTOMER: \_\_\_\_\_ THIS PORTION TO BE COMPLETED BY SIGNETICS  
 P.O. NO.: \_\_\_\_\_ PART NO.: \_\_\_\_\_  
 YOUR PART NO.: \_\_\_\_\_ S.D. NO.: \_\_\_\_\_  
 DATE: \_\_\_\_\_ DATE RECEIVED: \_\_\_\_\_

Word	OUTPUT				Word	OUTPUT				Word	OUTPUT				
	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>	
0					70					140					210
1					71					141					211
2					72					142					212
3					73					143					213
4					74					144					214
5					75					145					215
6					76					146					216
7					77					147					217
8					78					148					218
9					79					149					219
10					80					150					220
11					81					151					221
12					82					152					222
13					83					153					223
14					84					154					224
15					85					155					225
16					86					156					226
17					87					157					227
18					88					158					228
19					89					159					229
20					90					160					230
21					91					161					231
22					92					162					232
23					93					163					233
24					94					164					234
25					95					165					235
26					96					166					236
27					97					167					237
28					98					168					238



(8228)  
4096 BIT READ ONLY MEMORIES TRUTH TABLE/ORDER BLANK

CUSTOMER: \_\_\_\_\_ THIS PORTION TO BE COMPLETED BY SIGNETICS

P.O. NO.: \_\_\_\_\_ PART NO.: \_\_\_\_\_

YOUR PART NO.: \_\_\_\_\_ S.D. NO.: \_\_\_\_\_

DATE: \_\_\_\_\_ DATE RECEIVED: \_\_\_\_\_

Word	OUTPUT				Word	OUTPUT				Word	OUTPUT								
	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>					
280					350					420					490				
281					351					421					491				
282					352					422					492				
283					353					423					493				
284					354					424					494				
285					355					425					495				
286					356					426					496				
287					357					427					497				
288					358					428					498				
289					359					429					499				
290					360					430					500				
291					361					431					501				
292					362					432					502				
293					363					433					503				
294					364					434					504				
295					365					435					505				
296					366					436					506				
297					367					437					507				
298					368					438					508				
299					369					439					509				
300					370					440					510				
301					371					441					511				
302					372					442					512				
303					373					443					513				
304					374					444					514				
305					375					445					515				
306					376					446					516				
307					377					447					517				
308					378					448					518				



(8228)  
4096 BIT READ ONLY MEMORIES TRUTH TABLE/ORDER BLANK

CUSTOMER: \_\_\_\_\_ THIS PORTION TO BE COMPLETED BY SIGNETICS

P.O. NO.: \_\_\_\_\_ PART NO.: \_\_\_\_\_

YOUR PART NO.: \_\_\_\_\_ S.D. NO.: \_\_\_\_\_

DATE: \_\_\_\_\_ DATE RECEIVED: \_\_\_\_\_

Word	OUTPUT				Word	OUTPUT				Word	OUTPUT								
	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>					
560					630					700					770				
561					631					701					771				
562					632					702					772				
563					633					703					773				
564					634					704					774				
565					635					705					775				
566					636					706					776				
567					637					707					777				
568					638					708					778				
569					639					709					779				
570					640					710					780				
571					641					711					781				
572					642					712					782				
573					643					713					783				
574					644					714					784				
575					645					715					785				
576					646					716					786				
577					647					717					787				
578					648					718					788				
579					649					719					789				
580					650					720					790				
581					651					721					791				
582					652					722					792				
583					653					723					793				
584					654					724					794				
585					655					725					795				
586					656					726					796				
587					657					727					797				
588					658					728					798				



(8228)  
4096-BIT READ ONLY MEMORIES TRUTH TABLE/ORDER BLANK

CUSTOMER: \_\_\_\_\_ THIS PORTION TO BE COMPLETED BY SIGNETICS  
 P.O. NO.: \_\_\_\_\_ PART NO.: \_\_\_\_\_  
 YOUR PART NO.: \_\_\_\_\_ S.D. NO.: \_\_\_\_\_  
 DATE: \_\_\_\_\_ DATE RECEIVED: \_\_\_\_\_

Word	OUTPUT				Word	OUTPUT				Word	OUTPUT			
	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>
840					910					980				
841					911					981				
842					912					982				
843					913					983				
844					914					984				
845					915					985				
846					916					986				
847					917					987				
848					918					988				
849					919					989				
850					920					990				
851					921					991				
852					922					992				
853					923					993				
854					924					994				
855					925					995				
856					926					996				
857					927					997				
858					928					998				
859					929					999				
860					930					1000				
861					931					1001				
862					932					1002				
863					933					1003				
864					934					1004				
865					935					1005				
866					936					1006				
867					937					1007				
868					938					1008				





## ADVANCE INFORMATION

## DIGITAL 8000 SERIES TTL/MEMORY

### DESCRIPTION

The 82S09 is a 576 bit, TTL compatible, random access memory organized as 64 words by 9 bits per word. It is ideally suited for scratch pad, small buffer, and other applications where the number of words is limited and the number of bits per word is relatively large. The ninth bit provides a parity bit for 8 bits/word systems.

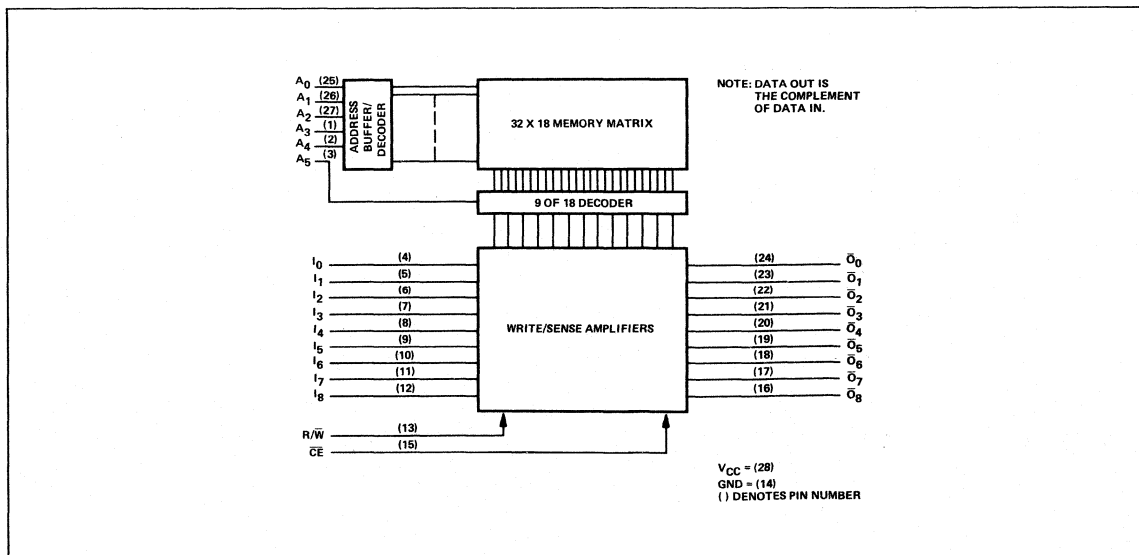
### FEATURES

- 64 X 9 ORGANIZATION
- 30 nSEC TYPICAL ACCESS TIME
- 1.5 mW/BIT TYPICAL POWER DISSIPATION
- 100μA INPUT LOAD
- OPEN-COLLECTOR OUTPUT

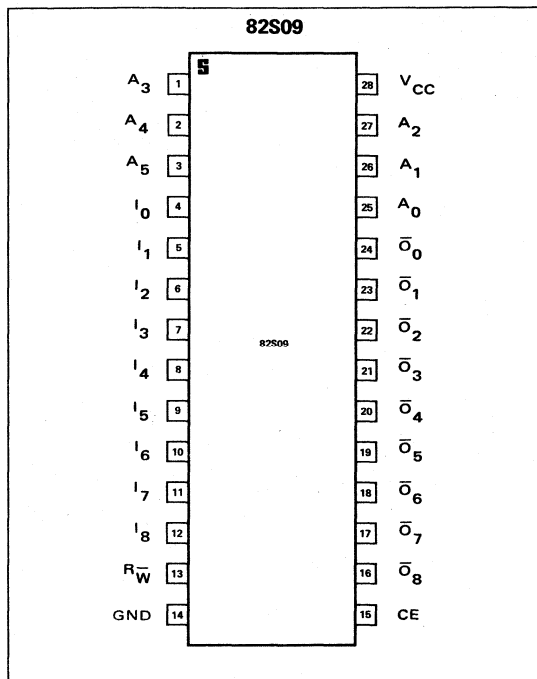
### APPLICATIONS

SCRATCH PAD  
BUFFER MEMORIES  
CONTROL STORE

### BLOCK DIAGRAM



### PIN CONFIGURATION (Top View)



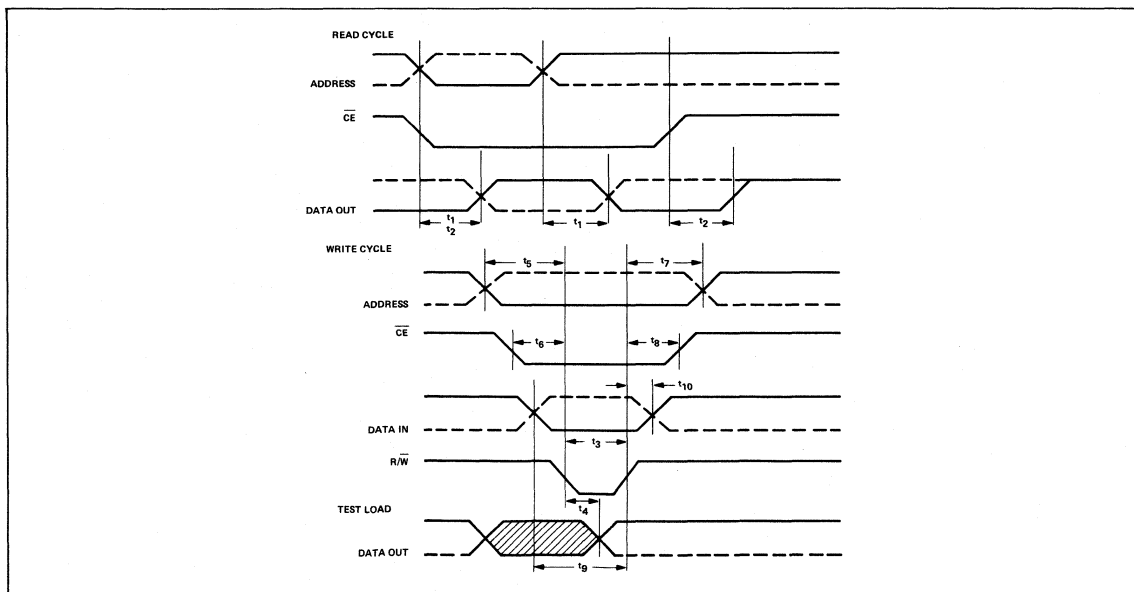
OBJECTIVE ELECTRICAL CHARACTERISTICS  $0 \geq T_A \geq 75^\circ\text{C}$ ,  $4.75 \geq V_{CC} \geq 5.25\text{V}$

CHARACTERISTIC	LIMITS			UNITS	TEST CONDITION
	MIN.	TYP.	MAX.		
"O" Input Current			-100	$\mu\text{A}$	$V_{IN} = 0.45\text{V}$ $V_{IN} = 5.25\text{V}$ $I_{IN} = 18\text{mA}$
"I" Input Current			25	$\mu\text{A}$	
Input Clamp Voltage			-1.2	Volts	
"O" Input Threshold			0.85	Volts	
"I" Input Threshold	2.0			Volts	$V_{OUT} = 5.5\text{V}$ $I_{OUT} = -6.4\text{mA}$
Output Leakage			40	$\mu\text{A}$	
"O" Output Voltage			0.5	Volts	
Power Supply Current		170	200	$\text{mA}$	

OBJECTIVE SWITCHING CHARACTERISTICS  $0 \geq T_A \geq 75^\circ\text{C}$ ,  $4.75 \geq V_{CC} \geq 5.25\text{V}$

CHARACTERISTIC	LIMITS			UNITS	TEST CONDITION
	MIN.	TYP.	MAX.		
Access Time					Data Stable Prior to Write
Address to Output $t_1$		35	50	nS	
$\overline{\text{CE}}$ to Output $t_2$		35	50	nS	
Write Pulse Width $t_3$	45			nS	
Write Access Time $t_4$		35	50	nS	
Address/ $\overline{\text{CE}}$ Set-Up $t_5/t_6$	10			nS	
Address/ $\overline{\text{CE}}$ Hold $t_7/t_8$	10			nS	
Data Set-Up $t_9$	50			nS	
Data Hold $t_{10}$	5			nS	

TIMING DIAGRAM





**signetics**

ECL 1,000/10,000  
PRODUCT  
SPECIFICATIONS

5



## ECL Functional Index

ECL 1,000/10,000 Product Information

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10118	Dual 2-Wide 3, 3-Input OR-AND Gate	5-59
10119	4-Wide 4, 3, 3, 3-Input OR-AND Gate Dual	5-61
10121	4-Wide 3,3,3,3-Input OR-AND/OR-AND-INVERT Gate	5-63
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## INTERFACE

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10115	Quad Differential Line Receiver	5-53
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10124	Quad Differential Line Driver Quad TTL to ECL Translator	5-65
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## MSI

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10161	1 of 8 Demultiplexer/Decoder (Selector Output is Low)	5-97
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10171	Dual 1 of 4 Demultiplexer/Decoder	5-106
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10190	Quad Differential Receiver/MST-ECL Translator	5-117
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## MEMORY

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10148	64 x 1 Random Access Memory (50 $\Omega$ Outputs)	5-87
10151	64 x 1 Random Access Memory with Latch	5-87



# signetics

ECL II  
EMITTER COUPLED LOGIC  
INTEGRATED CIRCUITS

PART NO.	REPLACES
N1004A	MC1004P
N1005A	MC1005P
N1006A	MC1006P
N1010A	MC1010P
N1011A	MC1011P
N1012A	MC1012P
N1013A	MC1013P
N1014A	MC1014P

PART NO.	REPLACES
N1015A	MC1015P
N1016A	MC1016P
N1017A	MC1017P
N1024A	MC1024P
N1025A	MC1025P
N1027A	MC1027P
N1033A	MC1033P
N1039B	MC1039P

## DESCRIPTION

The ECL II series of monolithic integrated logic circuits presents the system designer with an integrated circuit family designed to permit system implementation with a relatively small number of individual types. This approach offers cost savings, reduced power supply requirements, small physical size and high reliability.

ECL II circuits feature very fast propagation times relative to rise and fall times. This and the constant current feature impose fewer restrictions on system design, layout and fabrication than other high-speed families.

## FEATURES

- FULL REPLACEMENTS FOR MOTOROLA MECL II PARTS
- EXCELLENT NOISE IMMUNITY
- SIMULTANEOUS OR/NOR OUTPUTS
- HIGH FAN-IN AND FAN-OUT
- INTERNAL TEMPERATURE COMPENSATION

## APPLICATIONS

- HIGH SPEED DATA PROCESSORS
- DATA CONCENTRATORS
- CHARACTER RECOGNITION EQUIPMENT
- INSTRUMENTATION

REFER TO SECTION 9 FOR ECL II PACKAGE DESCRIPTIONS

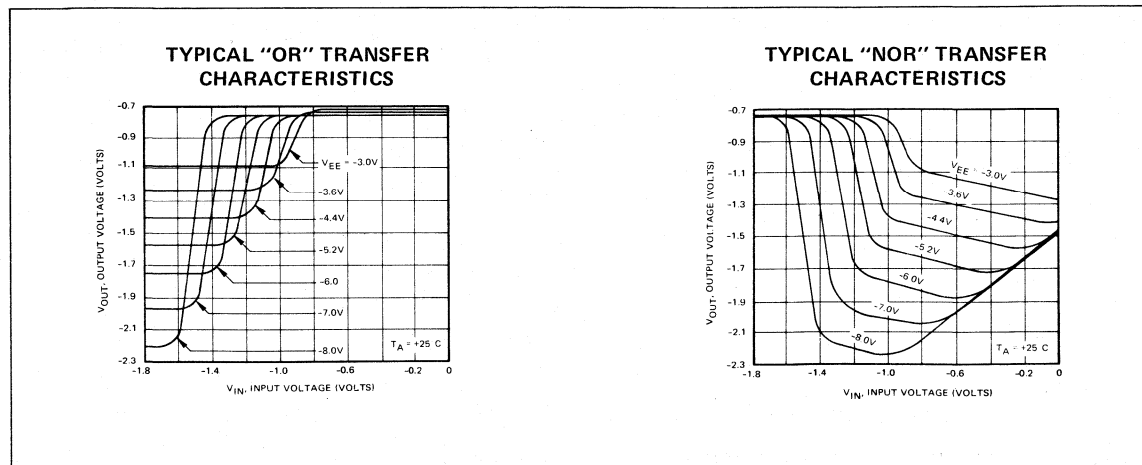
FUNCTION	PART NO. (0 to +75°C)	DC OUTPUT LOADING FACTOR	PROPAGATION DELAY nsec typ.	TOTAL POWER DISSIPATION mW typ.
Dual 4 Input Gate, 2 OR Outputs w/Pulldowns 2 NOR Outputs w/Pulldowns	N1004A	25	4.0	95
Dual 4 Input Gate, 2 OR Outputs w/Pulldowns 2 NOR Outputs w/o Pulldowns	N1005A	25	4.0	65
Dual 4 Input Gate, 2 OR Outputs w/o Pulldowns 2 NOR Outputs w/o Pulldowns	N1006A	25	4.0	45
Quad 2 Input Gate, 4 NOR Outputs w/Pulldowns	N1010A	25	4.5	115
Quad 2 Input Gate, 2 NOR Outputs w/Pulldowns 2 NOR Outputs w/o Pulldowns	N1011A	25	4.5	95
Quad 2 Input Gate, 4 NOR Outputs w/o Pulldowns	N1012A	25	4.5	65
AC Coupled J-K Flip-Flop (85MHz Typ.)	N1013A	25	6.0	125
Dual R-S Flip-Flop (Positive Clock)	N1014A	25	6.0	140
Dual R-S Flip-Flop (Negative Clock)	N1015A	25	6.0	140
Dual R-S Flip-Flop (Single Rail)	N1016A	25	6.0	140
Level Translator (Saturated Logic to ECL)	N1017A	25 (ECL)	15	105
Dual 2 Input Expandable Gate	N1024A	25	4.0	95
Dual 4 and 5 Input Expander	N1025A	—	—	—
AC Coupled J-K Flip-Flop (120 MHz Typ.)	N1027A	25	4.0	250
Dual R-S Flip-Flop (Single Rail, Negative Clock)	N1033A	25	6.0	140
Quad Level Translator (ECL to Saturated Logic)	N1039B	7 (DTL)	12	200

**DEFINITIONS**

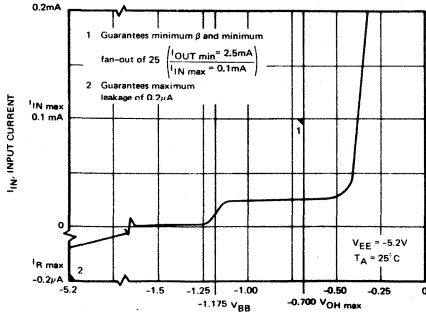
- $I_{in}$  Current drawn by the input of the test unit when a maximum logic "1" ( $V_{IH\ max}$ ) is applied at that input
- $I_{out}$  Output current
- $I_R$  Reverse current drawn from a transistor input of the test unit when  $V_{EE}$  is applied at that input
- $V_{BB}$  Bias reference supply voltage (-1.175 V nominal at 25°C)
- $V_{BE}$  Base-to-emitter voltage drop of a transistor
- $V_{CB}$  Collector-to-base voltage drop of a transistor
- $V_{CC}$  Most positive power supply voltage for a circuit

- $V_{EE}$  Most negative power supply voltage for a circuit
- $V_{in}$  Input voltage
- $V_{IH\ max}$  Maximum input logic "1" level voltage
- $V_{IH\ min}$  Minimum input logic "1" level (threshold) voltage
- $V_{IL\ max}$  Maximum input logic "0" level (threshold) voltage
- $V_{IL\ min}$  Minimum input logic "0" level voltage
- $V_{OH\ max}$  Maximum output "1" or high-level voltage
- $V_{OH\ min}$  Minimum output "1" high-level voltage
- $V_{OL\ max}$  Maximum output "0" or low-level voltage
- $V_{OL\ min}$  Minimum output "0" or low-level voltage
- $V_{out}$  Output voltage

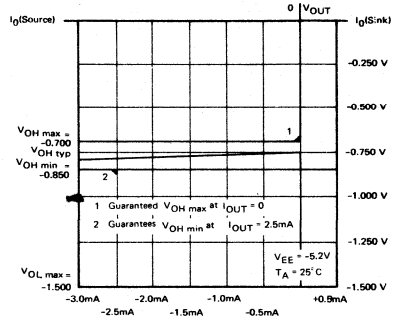
**TYPICAL CHARACTERISTIC CURVES**



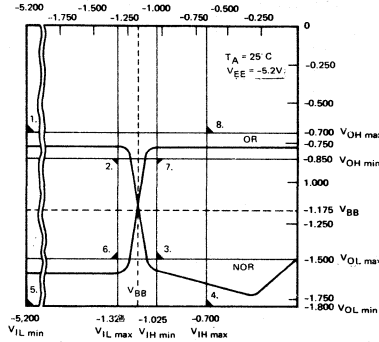
TYPICAL INPUT VOLTAGE VERSUS INPUT CURRENT



TYPICAL OUTPUT VOLTAGE VERSUS OUTPUT CURRENT



ECL II TRANSFER CHARACTERISTICS AND SPECIFICATION POINTS



ECL II WORST-CASE LEVELS

VOLTAGE LEVEL	AMBIENT TEMPERATURE				
	125°C	75°C	25°C	0°C	-55°C
V <sub>IH</sub> max	-0.530	-0.615	-0.700	-0.740	-0.825
V <sub>OH</sub> max	-0.530	-0.615	-0.700	-0.735	-0.825
V <sub>OH</sub> min	-0.700	-0.775	-0.850	-0.895	-0.990
V <sub>IH</sub> min	-0.875	-0.950	-1.025	-1.070	-1.165
V <sub>IL</sub> max	-1.205	-1.260	-1.325	-1.350	-1.405
V <sub>OL</sub> max	-1.380	-1.435	-1.500	-1.525	-1.580
V <sub>OL</sub> min	-1.720	-1.760	-1.800	-1.830	-1.890
V <sub>IL</sub> min	<V <sub>EE</sub>	<V <sub>EE</sub>	<V <sub>EE</sub>	<V <sub>EE</sub>	<V <sub>EE</sub>

$$\frac{\Delta V_{OH}}{\Delta V_{EE}} = 0.015 \text{ max}$$

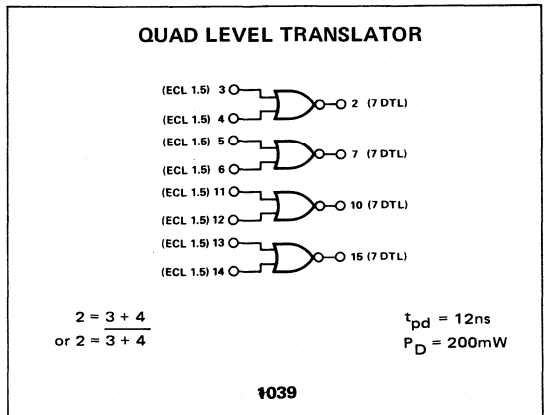
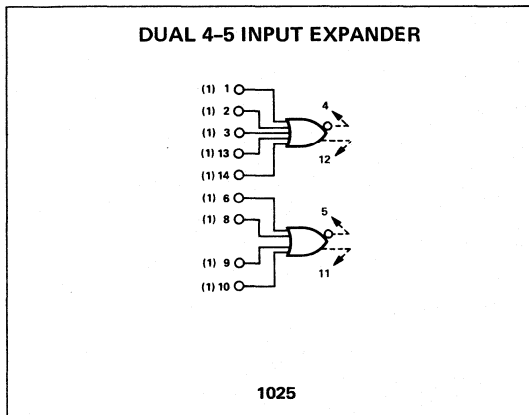
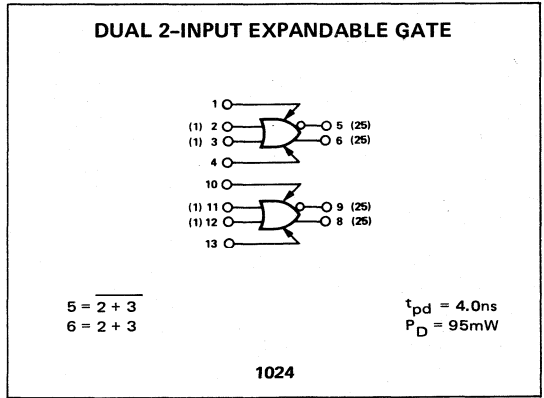
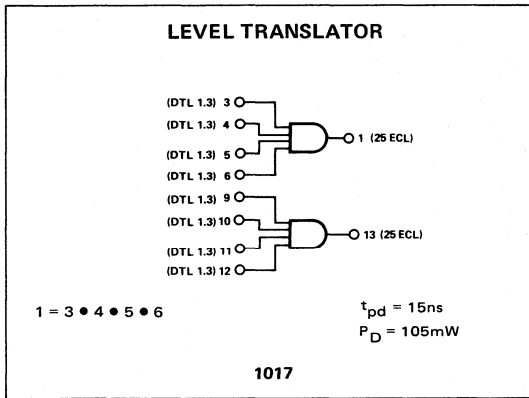
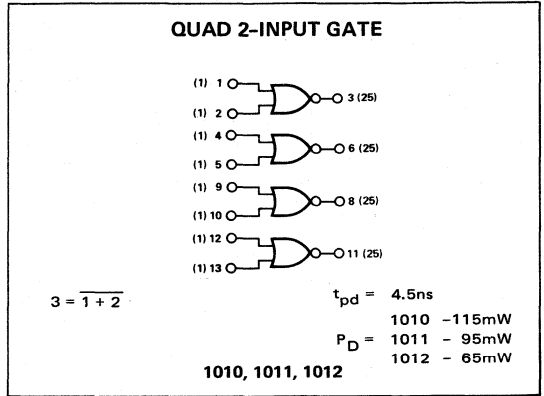
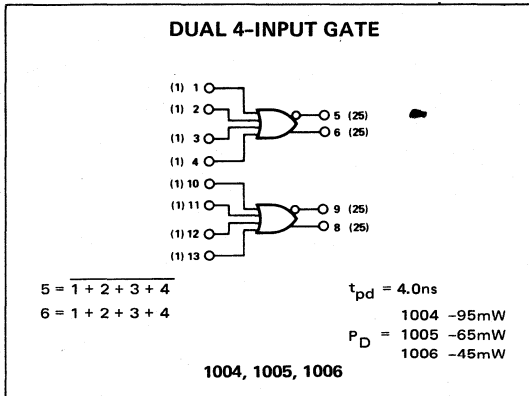
$$\frac{\Delta(V_{IH \text{ min}}, V_{IL \text{ max}})}{\Delta V_{EE}} = \begin{matrix} = 0.110 \text{ min} \\ = 0.115 \text{ nom} \\ = 0.120 \text{ max} \end{matrix}$$

$$\frac{\Delta(V_{OL \text{ max}}, V_{OL \text{ min}})}{\Delta V_{EE}} = \begin{matrix} = 0.210 \text{ min} \\ = 0.320 \text{ nom} \\ = 0.250 \text{ max} \end{matrix}$$

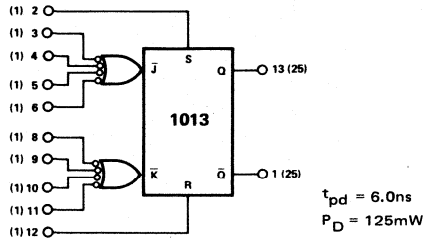
# SIGNETICS DIGITAL 1,000/10,000 SERIES ECL LOGIC DIAGRAMS

The logic diagrams shown describe the circuits of the ECL II line and permit quick selection of those circuits required to implement a particular logic system. Logic equations, truth tables, typical propagation delay time ( $t_{pd}$ ), and typical power dissipation per package ( $P_D$ ) are provided to show line compatibility. Package pin numbers and dc loading

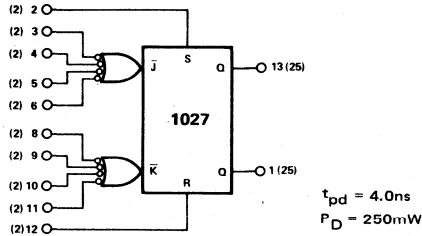
factors are specified on each logic diagram. Numbers at the ends of the terminals are package pin numbers. Numbers in parenthesis indicate dc loading factors at each terminal. ECL II circuits contain internal bias networks, insuring that the transition point is always in the center of the transfer characteristic curves over the temperature range.



AC COUPLED J-K FLIP-FLOP (85 MHz TYP)



AC COUPLED J-K FLIP-FLOP (120 MHz TYP)



CLOCKED J-K OPERATION

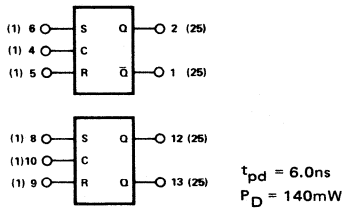
J	K	$\overline{C_D}$	$Q^n$
$\phi$	$\phi$	0	$Q^n$
0	0	1	$\overline{Q^n}$
0	1	1	1
1	0	1	0
1	1	1	$Q^n$

The  $\overline{J}$  and  $\overline{K}$  inputs refer to logic levels while the  $\overline{C_D}$  input refers to logic swings. The J and K inputs should be changed to logical "1" only while the  $\overline{C_D}$  input is in a logic "1" state. ( $\overline{C_D}$  maximum "1" level =  $V_{CC} - 0.6V$ ) Clock  $\overline{C_D}$  is obtained by tying one  $\overline{J}$  and one K input together.

R-S OPERATION

R	S	$Q^{n+1}$
0	1	1
1	0	0
0	0	$Q^n$
1	1	ND

DUAL CLOCKED R-S FLIP-FLOP



1014 1015

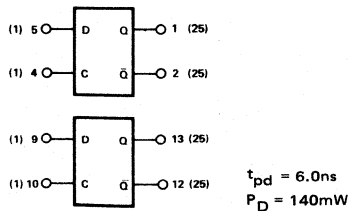
1014

C	R	S	$Q^{n+1}$
1	0	0	$Q^n$
1	0	1	1
1	1	0	0
1	1	1	ND
0	$\phi$	$\phi$	$Q^n$

1015

C	R	S	$Q^{n+1}$
0	0	0	$Q^n$
0	0	1	1
0	1	0	0
0	1	1	ND
1	$\phi$	$\phi$	$Q^n$

DUAL CLOCKED SINGLE RAIL R-S FLIP-FLOP



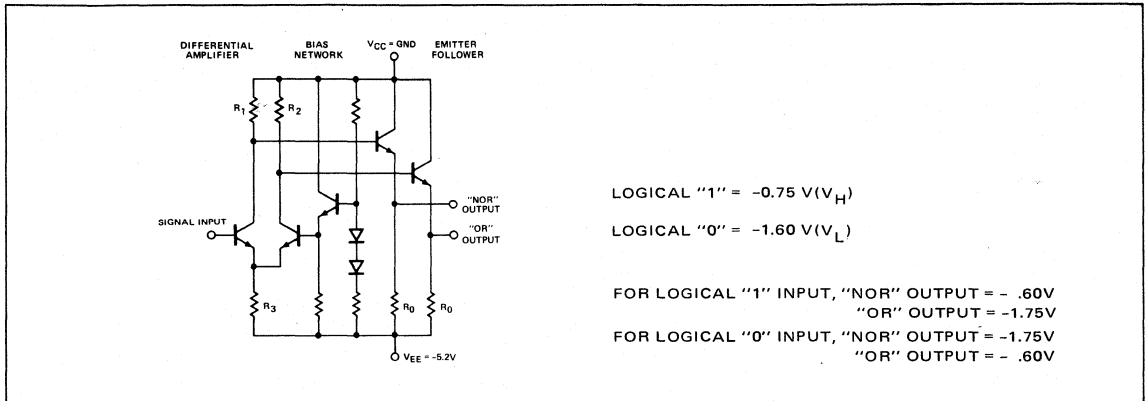
1016 1033

1016

C	D	$Q^{n+1}$
0	0	$Q^n$
0	1	$Q^n$
1	0	0
1	1	1

1033

C	D	$Q^{n+1}$
1	0	$Q^n$
1	1	$Q^n$
0	0	0
0	1	1



MAXIMUM RATINGS

Characteristic	Symbol	Rating	Unit
<b>Ratings above which device life may be impaired:</b>			
Power Supply Voltage (V <sub>CC</sub> =0)	V <sub>EE</sub>	-10	V <sub>DC</sub>
Input Voltage (V <sub>CC</sub> =0)	V <sub>IN</sub>	0 to V <sub>EE</sub>	V <sub>DC</sub>
Output Source Current	I <sub>O</sub>	0 to +25	mAdc
Storage Temperature Range	T <sub>stg</sub>	-55 to +125	°C
<b>Recommended maximum ratings above which performance may be degraded:</b>			
Operating Temperature Range	T <sub>A</sub>	0 to +75	°C
AC Fan-in (Expandable Gates)	m	20	-
AC Fan-Out* (Gates and Flip-Flops)	n	15	-

\*Although a minimum dc fan-out of 25 is guaranteed in each electrical specification, it is recommended that the maximum ac fan-out of 15 be used for high-speed operation.

The ECL II line of monolithic integrated logic circuits was designed as a non-saturating form of logic which eliminates transistor storage time as a speed limiting characteristic.

The typical ECL II circuit comprises a differential-amplifier input with internal bias reference and with emitter-follower output to restore dc levels. High fan-out operation is possible because of high input impedance of the differential amplifier and low output impedance of the emitter followers. Power supply noise is virtually eliminated by the nearly constant current drain of the differential amplifier, even during transition time. Basic gate design provides for simultaneous output of both the function and its complement.

As shown in the schematic above, it is recommended that -5.2V be applied at V<sub>EE</sub> with V<sub>CC</sub> = Gnd.

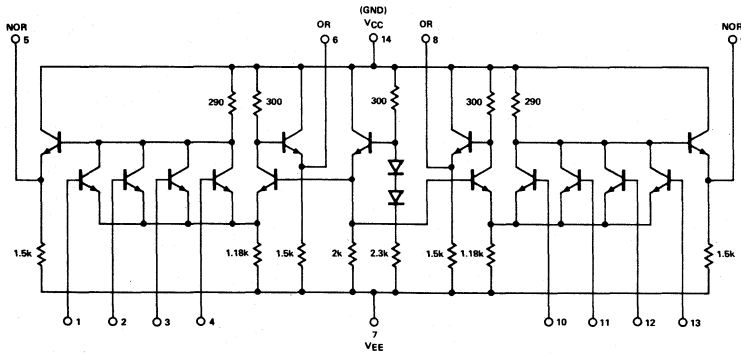
The nominal output logic swing of 0.85V varies from a low state of V<sub>L</sub> = -1.60V to a high state of V<sub>H</sub> = -0.75V.

An internal voltage of -1.175V is applied to the "bias input" of the differential amplifier and the logic signals are applied to the "signal input". If a logical "0" is applied, the current through R<sub>3</sub> is supplied by the internally biased transistor. A drop of 0.85V occurs across R<sub>2</sub>. The OR output then is -1.60V, one V<sub>BE</sub> drop below 0.85V. Since no current flows in the "signal input" transistor, the NOR output is a V<sub>BE</sub> drop below ground, -0.75V. When a logical "1" level is applied to the "signal input", the current through R<sub>2</sub> is switched to the "signal input" transistor and a drop of 0.85V occurs across R<sub>1</sub>. The OR output then goes to -0.75V, and the NOR output goes to -1.60V.

NOTE: Unused inputs should be connected to V<sub>EE</sub>.

The voltage applied to the bias input is obtained from an internal regulated, temperature-compensated bias network. The temperature characteristics of the bias network compensate for variations in circuit operating point over the temperature range or supply voltage changes, and insure that the threshold point is in the center of the transfer characteristic curves.

DUAL 4-INPUT GATES



1004 Shown

1005

Omit NOR output  
pulldown resistors

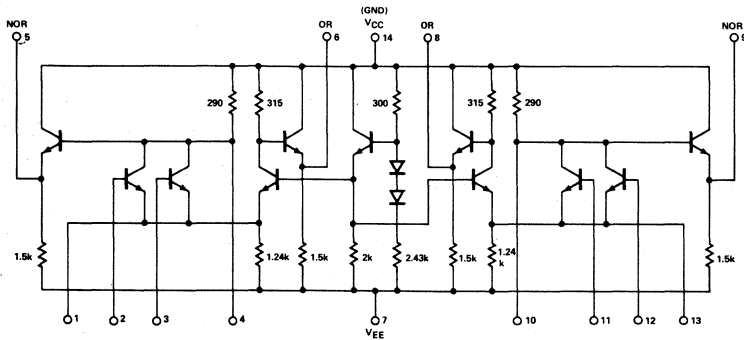
1006

Omit all output  
pulldown resistors

Resistor values are nominal

1004 THRU 1006

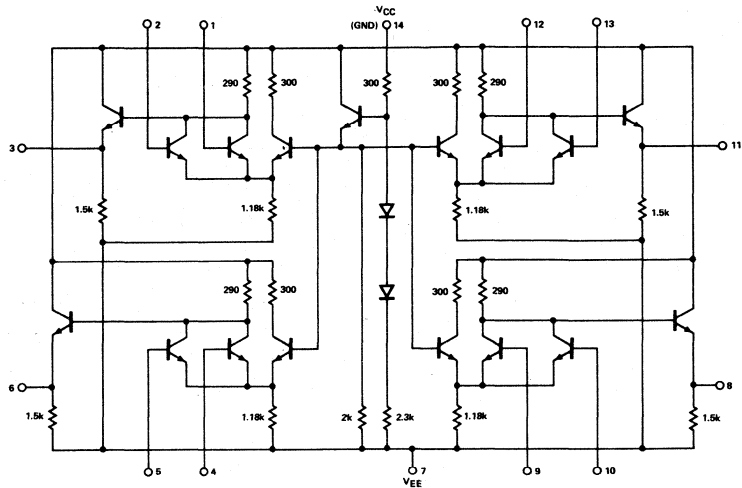
DUAL 2-INPUT EXPANDABLE GATE



Resistor values are nominal

1024

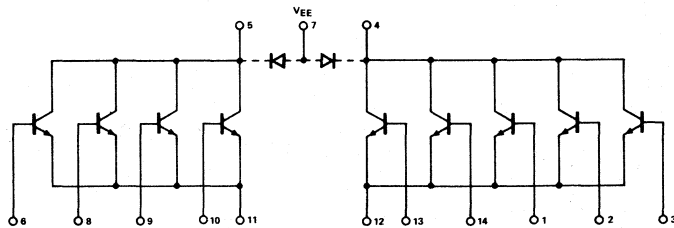
QUAD 2-INPUT GATES



1010 Shown  
 1011  
 Omit pulldown resistors  
 on pins 3 and 6  
 1012  
 Omit all output  
 pulldown resistors  
 Resistor values are nominal

1010 THRU 1012

DUAL 4-5 INPUT EXPANDER

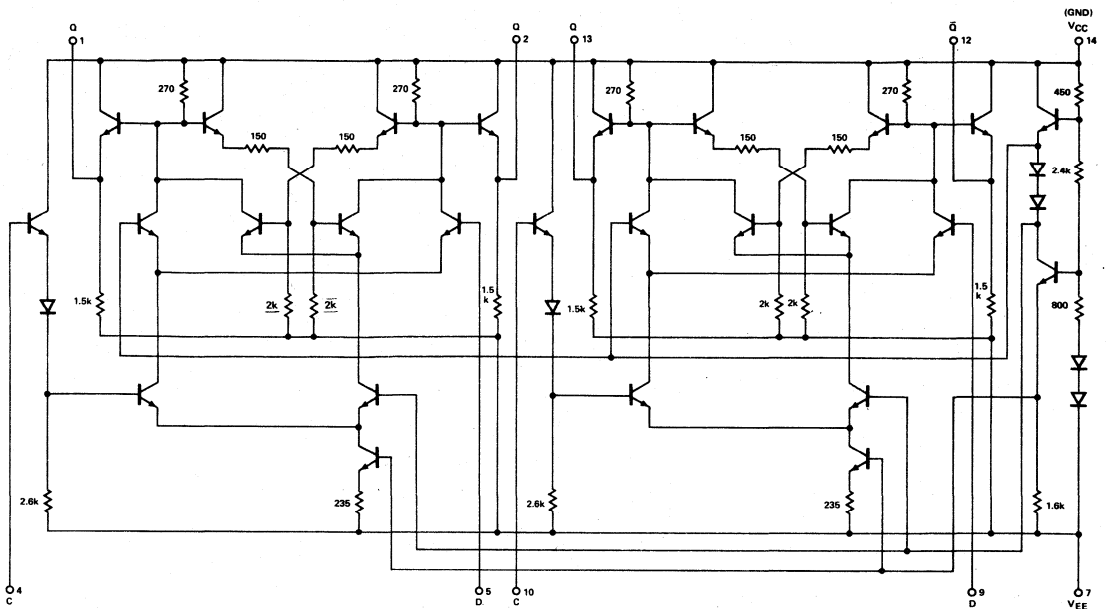


Resistor values are nominal

1025



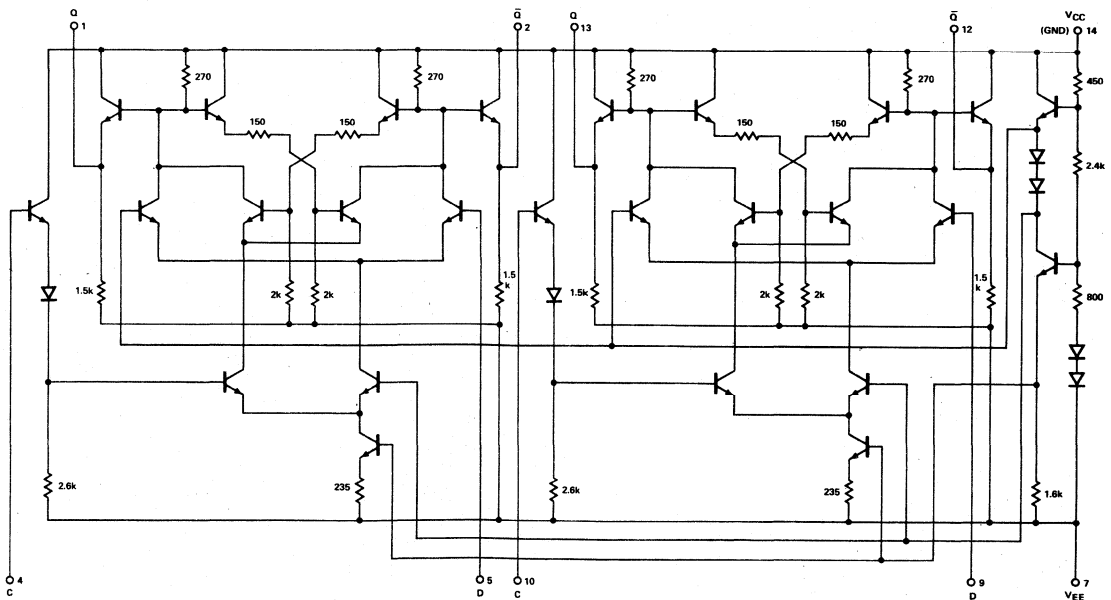
DUAL R-S FLIP-FLOP WITH SINGLE RAIL INPUT AND POSITIVE CLOCK



Resistor values are nominal

1016

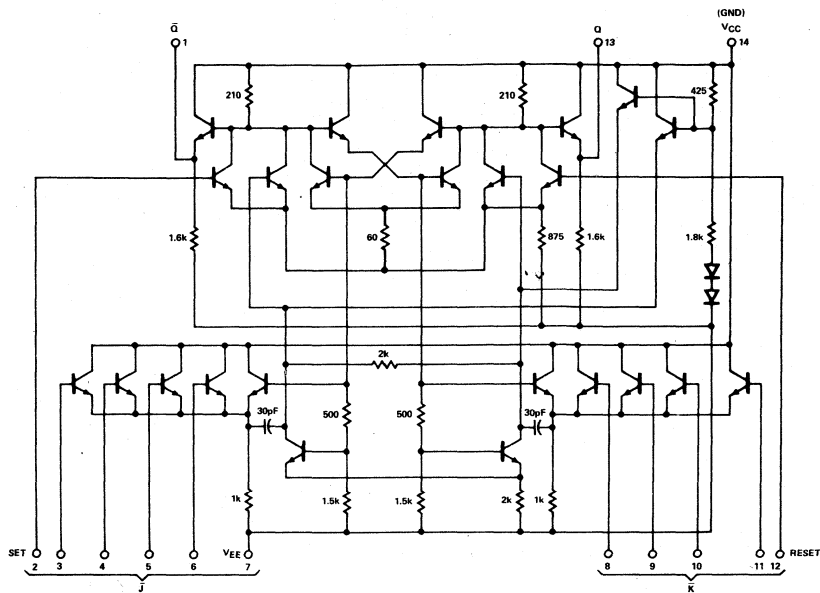
DUAL R-S FLIP-FLOP WITH SINGLE RAIL INPUT AND NEGATIVE CLOCK



Resistor values are nominal

1033

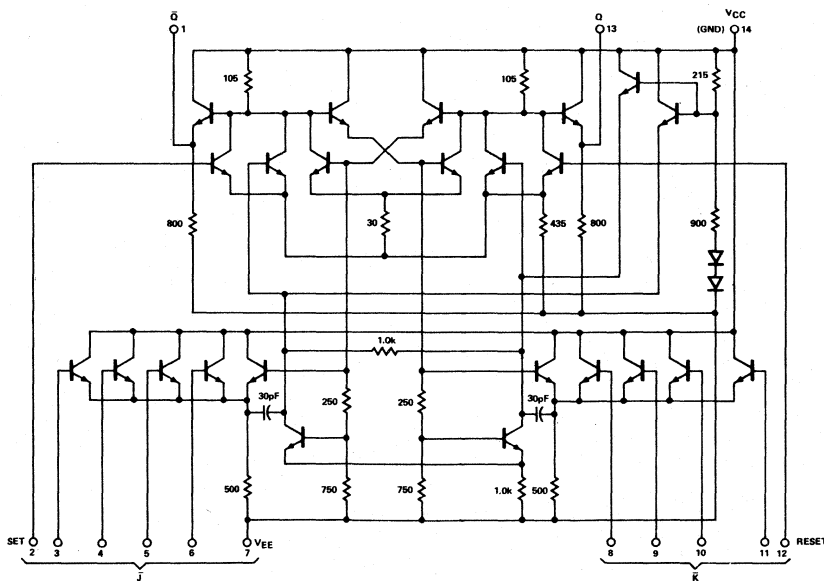
85-MHz AC-COUPLED J-K FLIP-FLOP



Resistor values are nominal

1013

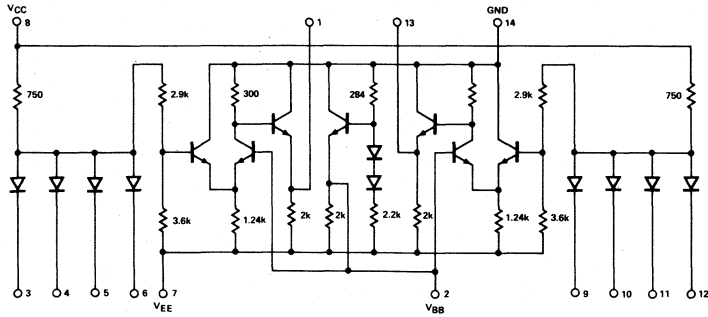
120-MHz AC-COUPLED J-K FLIP FLOP



Resistor values are nominal

1027

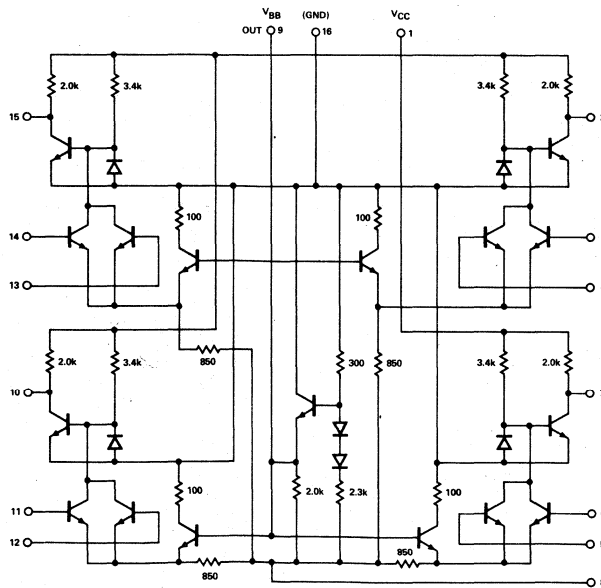
**SATURATED LOGIC-TO-ECL DUAL TRANSLATOR**



Resistor values are nominal

1017

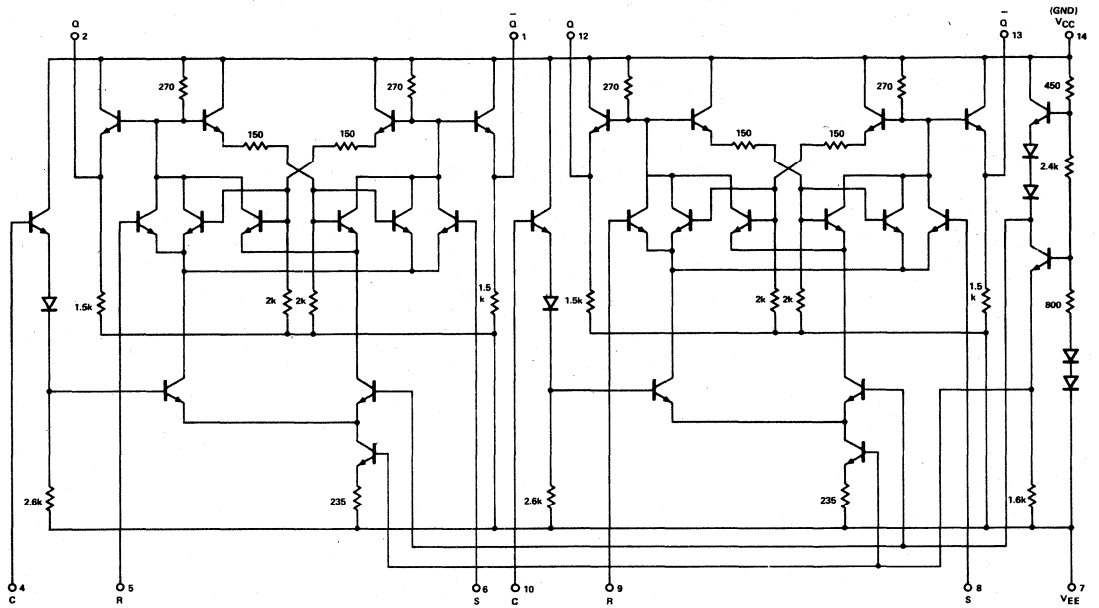
**ECL-TO-SATURATED LOGIC QUAD TRANSLATOR**



Resistor values are nominal

1039

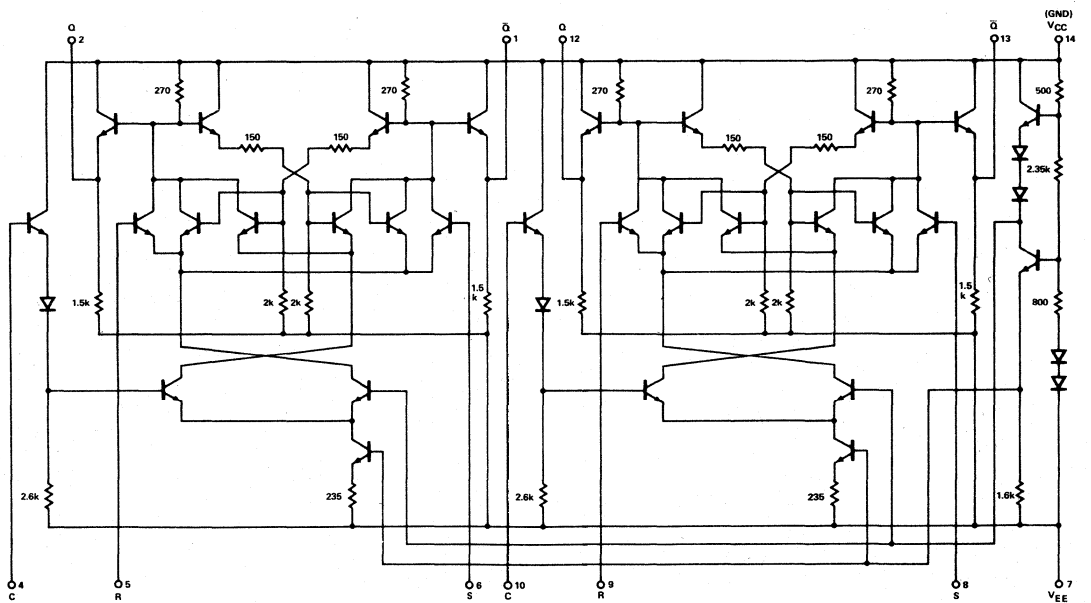
DUAL R-S FLIP-FLOP WITH POSITIVE CLOCK



Resistor values are nominal

1014

DUAL R-S FLIP-FLOP WITH NEGATIVE CLOCK



Resistor values are nominal

1015

N1068B: 0 to +75°C

## DIGITAL 10,000 SERIES ECL

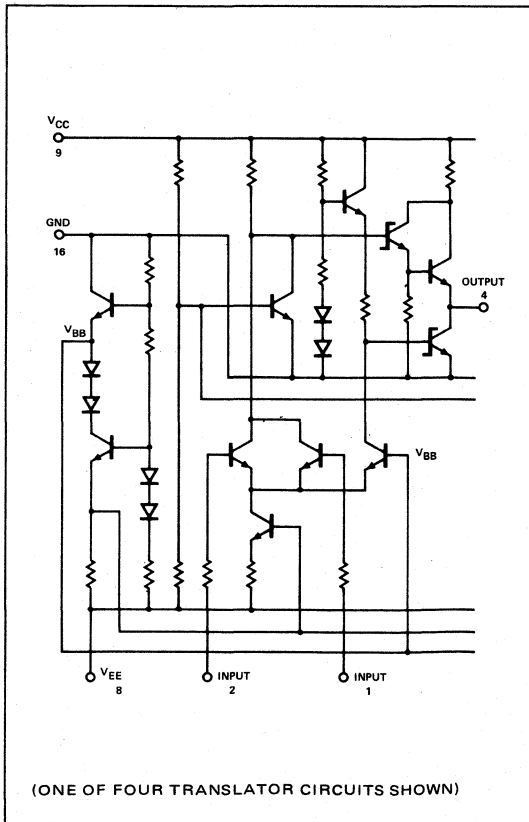
### DESCRIPTION

Four level translators for converting ECL signal levels to TTL or DTL logic levels. The 1068 incorporates familiar Schottky "totem pole" outputs to provide high speed operation.

### FEATURES

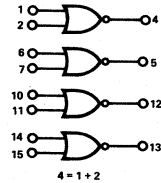
- FAST PROPAGATION DELAY = 5.0 ns TYP
- POWER DISSIPATION = 360 mW/PACKAGE TYP
- SCHOTTKY TTL TOTEM POLE OUTPUTS
- RECOMMENDED POWER SUPPLIES:  
 $V_{CC} = +5.0 \text{ V DC } \pm 5\%$   
 $V_{EE} = -5.2 \text{ V DC } \pm 5\%$
- FOUR TRANSLATORS PER PACKAGE

### CIRCUIT SCHEMATIC

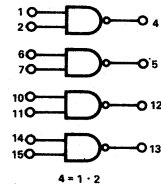


### LOGIC DIAGRAM AND PIN CONFIGURATION

#### POSITIVE LOGIC



#### NEGATIVE LOGIC



Gnd = 16  
 $V_{CC} (+5.0 \text{ Vdc}) = 9$   
 $V_{EE} (-5.2 \text{ Vdc}) = 8$

DC Input Loading Factor = 2.5 (ECL)  
 DC Output Loading Factor = 10 (TTL)

**ELECTRICAL CHARACTERISTICS**

Test procedures are shown for one translator. The other translators are tested in the same manner.

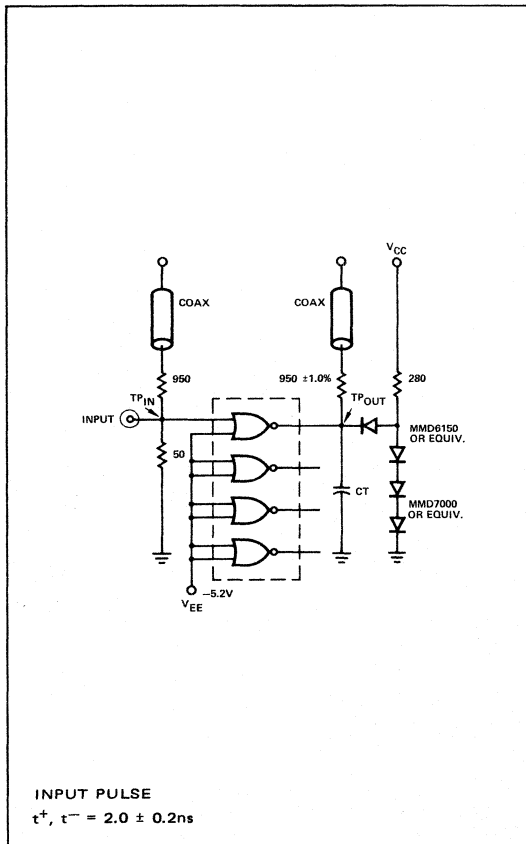
@ Test Temperature  
 0° C  
 1068 +25° C  
 75° C

		TEST VOLTAGE/CURRENT VALUES											
		Volts										mAdc	
		V <sub>IL</sub> min to V <sub>IL</sub> max	V <sub>IH</sub> min to V <sub>IH</sub> max	V <sub>IH</sub> max	V <sub>CC</sub>	V <sub>EE</sub>	I <sub>OL</sub>	I <sub>OH</sub>					
0° C		-5.2 to -1.375	-1.045 to -0.740	-	+5.0	-5.2	2	-2.0					
+25° C		-5.2 to -1.350	-1.000 to -0.700	-0.700	+5.0	-5.2	20	-2.0					
75° C		-5.2 to -1.285	-0.925 to -0.625	-	+5.0	-5.2	20	-2.0					

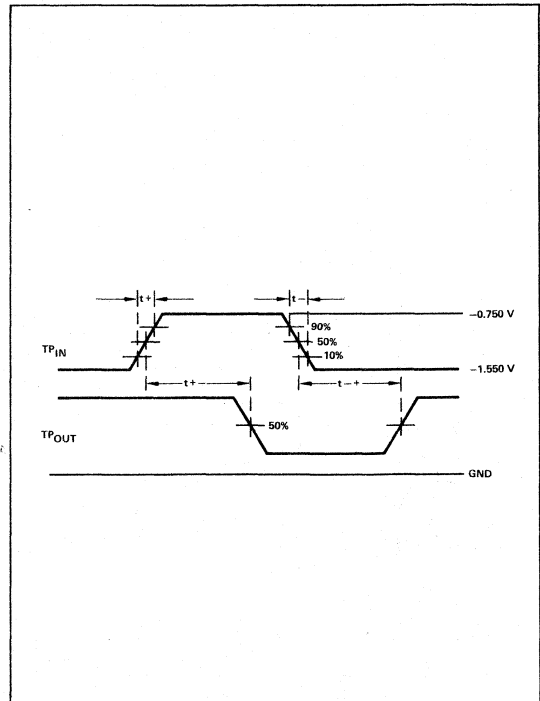
  

		TEST VOLTAGE/CURRENT APPLIED TO PINS LISTED BELOW:											
		V <sub>IL</sub> min to V <sub>IL</sub> max	V <sub>IH</sub> min to V <sub>IH</sub> max	V <sub>IH</sub> max	V <sub>CC</sub>	V <sub>EE</sub>	I <sub>OL</sub>	I <sub>OH</sub>					
Positive Supply	ICCH	9	-	-	1,2,6,7,10,14,15	9	8	-	-	-	-	16	
Drain Current	ICCL	9	-	-	45	9	1,2,6,7,8,10,11,14,15	-	-	-	-	16	
Negative Supply	IE	8	-	-	50	-	1,2,6,7,8,10,11,14,15	-	-	-	-	16	
Drain Current													
Input Current	I <sub>in</sub>	1	-	-	250	-	1	-	-	-	-	16	
		2	-	-	250	-	2	-	-	-	-	16	
Input Leakage Current	I <sub>R</sub>	1	-	-	0.5	-	1.0	-	-	-	-	16	
		2	-	-	0.5	-	1.0	-	-	-	-	16	
Output Voltage High	V <sub>OH</sub>	4	2.4	-	2.4	-	2.4	-	9	8	-	3 16	
		4	2.4	-	2.4	-	2.4	-	9	8	-	3 16	
Output Voltage Low	V <sub>OL</sub>	4	-	0.5	-	0.5	-	0.5	9	2,6,7,8,10,11,14,15	3	- 16	
		4	-	0.5	-	0.5	-	0.5	9	1,6,7,8,10,11,14,15	3	- 16	
Output Short Circuit Current	I <sub>SC</sub>	4	-30	-90	-30	-90	-30	-90	9	1,2,6,7,8,10,11,14,15	-	- 3,16	
			Typ	Max	Typ	Max	Typ	Max					
Switching Times	t <sub>1-4+</sub>	4	-	-	5.0	-	-	-	9	2,6,7,8,10,11,14,15	-	- 16	
	t <sub>1+4-</sub>	-	-	-	-	-	-	-	9	2,6,7,8,10,11,14,15	-	- 16	
	t <sub>2-4+</sub>	-	-	-	-	-	-	-	9	1,6,7,8,10,11,14,15	-	- 16	
	t <sub>2+4-</sub>	-	-	-	-	-	-	-	9	1,6,7,8,10,11,14,15	-	- 16	

**SWITCHING TIME TEST CIRCUIT**



**WAVEFORM @ 25° C**



The coax delays from input to scope and output to scope must be matched. The scope must be terminated in 50-ohm impedance. The 950-ohm resistor and the scope termination impedance constitute a 20:1 attenuator probe. Coax shall be CT-070-50 or equivalent.  
 $C_T = 25$  pF = total parasitic capacitance, which includes probe, wiring, and load capacitances.

ECL 1,000/10,000 SERIES PRODUCT INFORMATION

10,000 SERIES ADVANTAGES

- Best system cost — Performance available in a standard integrated circuit family.
- Factor of 2-or-more — higher system performance than Schottky TTL.
- Complete family of SS1, interface elements, and high performance MS1, with memories coming soon.
- ECL 10,000 Series includes MECL 10,000 equivalents and Signetics-originated 10,000 Series designs.
- Offers designers the logic power of ECL — Open emitter logic, simultaneous complementary outputs, transmission line capability.
- Offers designers system-optimized circuit characteristics — Excellent speed power product, excellent propagation delay/rise time ratio, excellent noise immunity/noise generation ratio, transmission line capability, differential interface capability, and high immunity from power supply variations ( $\pm 5\%$  recommended,  $\pm 10\%$  results in minimal change in system characteristics).
- Compatible with transmission line environment, two-sided printed circuit boards, standard fan cooling techniques. Less support hardware required than Schottky TTL for many system designs.
- Low noise generation capability — Complementary balanced-load outputs, optimized propagation delay/rise time ratio, minimum "1"/"0" power imbalance.
- Directly compatible with MECL III family. Also compatible with ECL II/MECL II family with some reduction in noise immunity at the interface.
- These products contain a temperature compensated internal bias which ensures that the threshold point tracks with the center of the transition region over temperature.

10,000 SERIES TECHNOLOGY

- Signetics thin-epitaxial high performance, high volume production process.
- Advanced circuit design techniques used:  
Internal Emitter-Dot 'OR' Logic  
Internal Collector-Dot 'AND' Logic  
Internal Stacked Series Gating  
Single Stage Delay Exclusive OR Gates

PACKAGE INFORMATION

**B PACKAGE**

**NOTES:**

1. Lead Material: Nickel, tin plated
2. Body Material: Silicone molded
- ③ Tolerances non-cumulative
- ④ Signetics symbol denotes Lead No. 1
- ⑤ Lead spacing shall be measured within this zone
6. Body dimensions do not include molding flash

PACKAGE TYPES

- SSI, MSI and memories will be available in cerdip packages. Signetics new designation F specifies cerdip packages or any number of leads. (Previously E specified 16 lead cerdip).
- Presently SSI, and later some MSI and memories will be available in Signetics' double-encapsulated silicone dip with nickel lead frame. This provides minimum thermal resistance and hence maximum thermal compatibility with cerdip packages.

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Power Supply Voltage ( $V_{CC} = 0$ )	Note 1	$V_{EE}$ -8	Vdc
Input Voltage ( $V_{CC} = 0$ )	Note 1	$V_{IN}$ 0 to $V_{EE}$	Vdc
Output Source Current	Note 1	$I_o$	
Continuous		50	mAdc
Surge		100	mAdc
Storage Temperature Range	Note 1	$T_{stg}$ -55 to +125	$^{\circ}C$
Operating Junction Temperature	Note 1	$T_J$ 125	$^{\circ}C$
Operating Temperature Range	Note 2	$T_A$ -30 to +85	$^{\circ}C$
DC Fan-Out (Gates and Flip-Flops)	Notes 2,3	70	—
Power Supply Regulation Required	Note 2	$\pm 10\%$	—

NOTES:

1. Ratings above which device life may be impaired.
2. Recommended maximum rating above which performance may be degraded.
3. AC fan-out is defined by desired system performance.

ORDERING INFORMATION

- 101XX F Specifies a 10,000 Series product in Cerdip Dual-in-Line package, operating temperature range  $-30^{\circ}C$  to  $+85^{\circ}C$  (intermediate Range). (F is Signetics' new designation for Cerdip).
- 101XX B Specifies a 10,000 Series product in 16 pin Silicone Dual-in-Line package, operating temperature range  $-30^{\circ}C$  to  $+85^{\circ}C$  (intermediate Range).

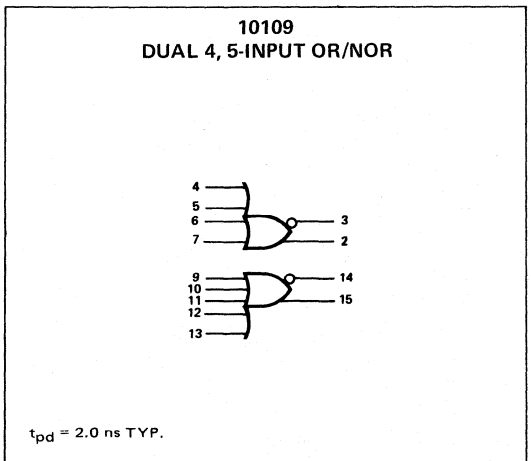
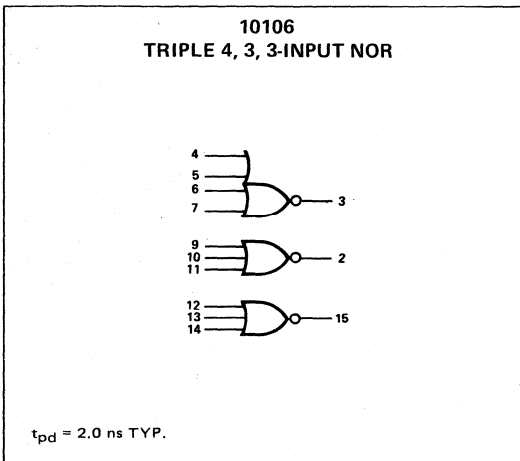
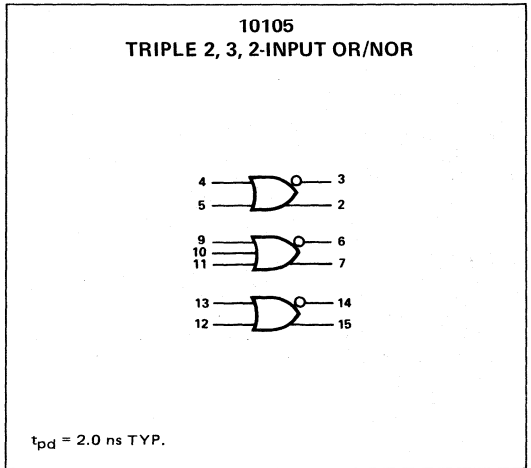
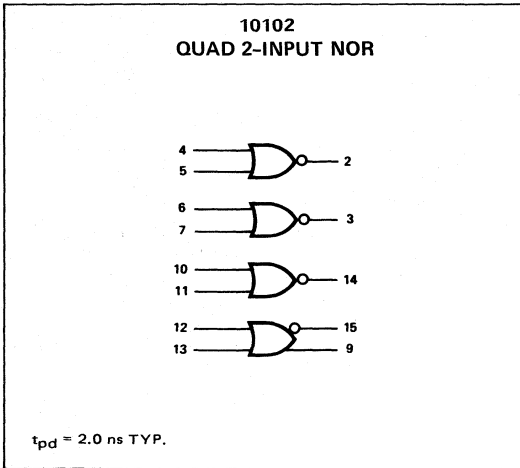
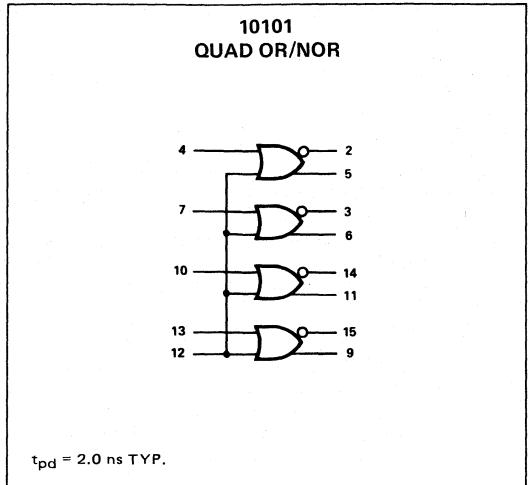
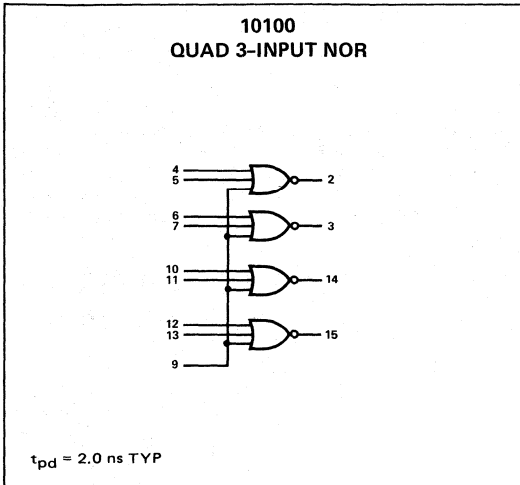
Availability of a device in a particular package is indicated on the appropriate product Data Sheet.

**F PACKAGE**

**NOTES:**

1. Lead Material: Alloy 42 or equivalent, tin plated
2. Body Material: Ceramic with glass seal
- ③ Tolerances non-cumulative
- ④ Signetics symbol denotes lead No. 1
- ⑤ Lead spacing shall be measured within this zone

LOGIC DIAGRAMS: BASIC GATES



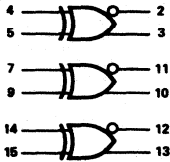
NOTES:  $V_{CC1} = 1, V_{CC2} = 16, V_{EE} = 8$

POSITIVE LOGIC: HIGH LEVEL = '1'



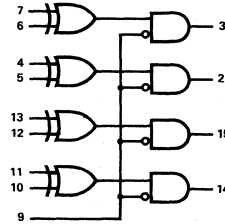
LOGIC DIAGRAMS: COMPLEX GATES

**10107**  
TRIPLE EXCLUSIVE OR/NOR



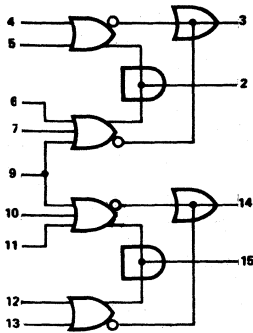
$t_{pd} = 2.0, 2.8 \text{ ns TYP.}$

**10113**  
QUAD EXCLUSIVE OR (WITH ENABLE)



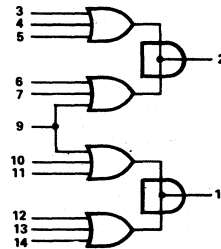
$t_{pd} = 2.5 \text{ ns TYP.}$

**10117**  
DUAL 2-WIDE 2, 3-INPUT OA/OAI GATE



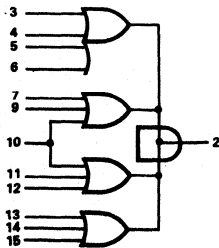
$t_{pd} = 2.3 \text{ ns TYP.}$

**10118**  
DUAL 2-WIDE 3-INPUT OR-AND



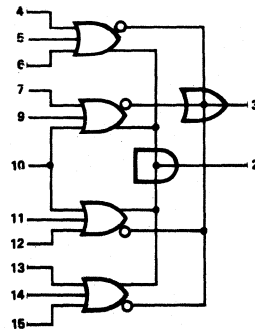
$t_{pd} = 2.3 \text{ ns TYP.}$

**10119**  
4-WIDE 4, 3, 3, 3-INPUT OR-AND



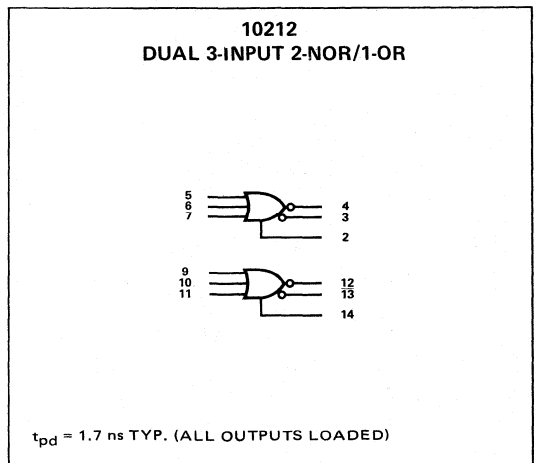
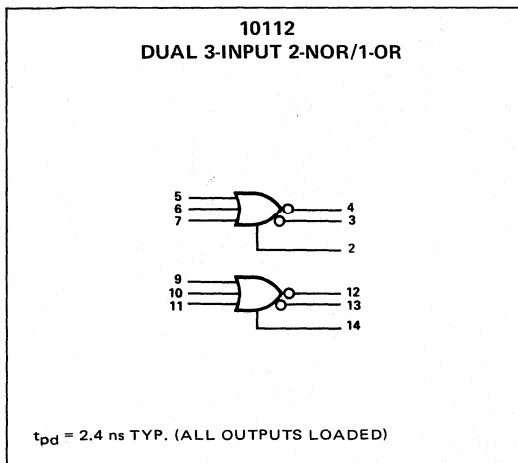
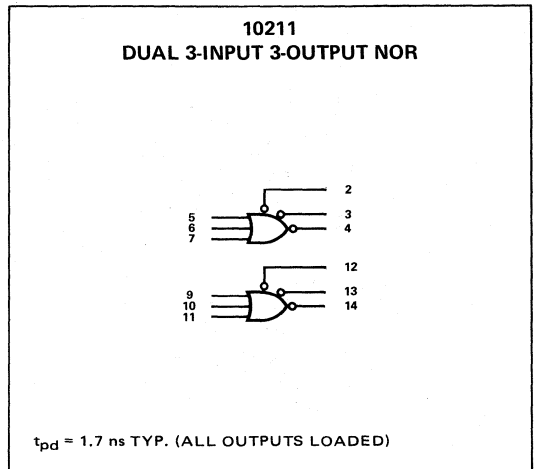
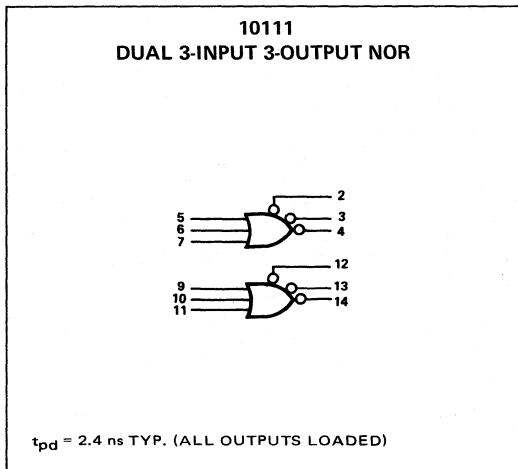
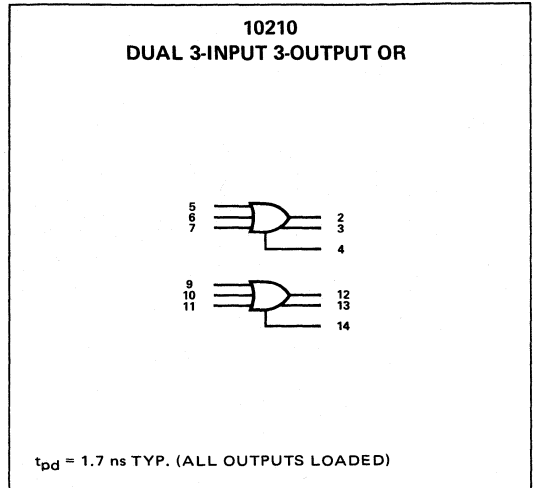
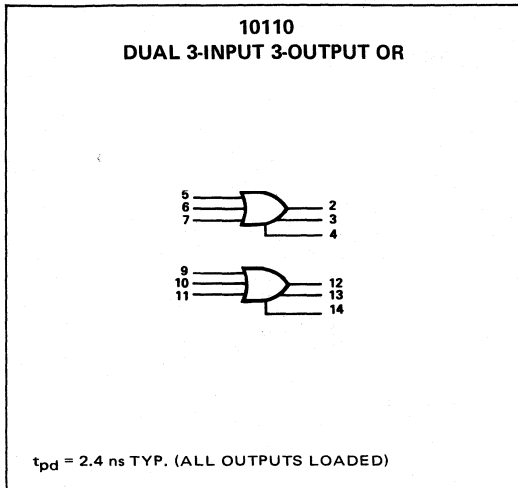
$t_{pd} = 2.3 \text{ ns TYP.}$

**10121**  
4-WIDE 3, 3, 3, 3-INPUT OA/OAI



$t_{pd} = 2.3 \text{ ns TYP.}$

LOGIC DIAGRAMS: MULTIPLE OUTPUT GATES

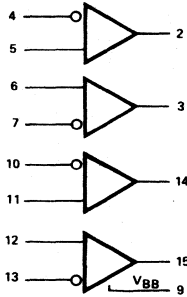


NOTES:  $V_{CC1} = 1, 15, V_{CC2} = 16, V_{EE} = 8$

POSITIVE LOGIC: HIGH LEVEL = '1'

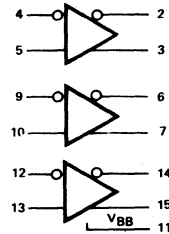
LOGIC DIAGRAMS: INTERFACE CIRCUITS

**10115**  
**QUAD DIFFERENTIAL**  
**LINE RECEIVER**



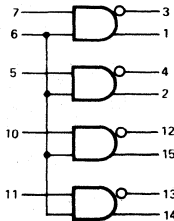
$t_{pd} = 2.0 \text{ ns TYP.}$   
 $V_{CC1} = 1, V_{CC2} = 16, V_{EE} = 8$

**10116**  
**TRIPLE DIFFERENTIAL**  
**LINE RECEIVER (OR/NOR)**



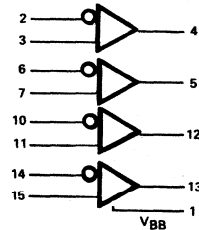
$t_{pd} = 2.0 \text{ ns TYP.}$   
 $V_{CC1} = 1, V_{CC2} = 16, V_{EE} = 8$

**10124**  
**QUAD TTL TO-ECL TRANSLATOR**



$t_{pd} = 5.0 \text{ ns TYP.}$   
 $V_{CC} = 9 \text{ GND} = 16 \text{ } V_{EE} = 8$

**10125**  
**QUAD ECL TO TTL TRANSLATOR**  
**(TOTEM-POLE OUTPUTS)**

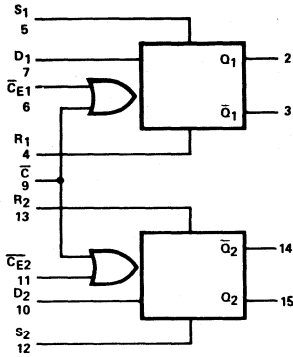


$t_{pd} = 5.0 \text{ ns TYP.}$   
 $V_{CC} = 9 \text{ GND} = 16 \text{ } V_{EE} = 8$

NOTE: POSITIVE LOGIC: HIGH LEVEL = '1'

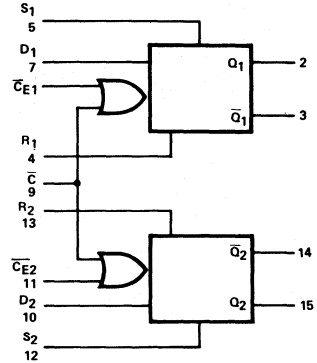
LOGIC DIAGRAMS: DUAL LATCHES AND FLIP-FLOPS

10130  
DUAL D-TYPE LATCH



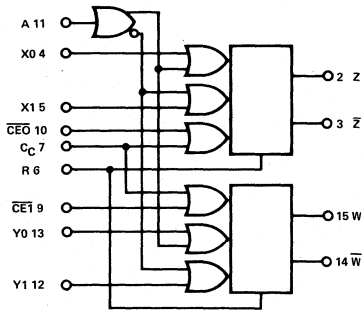
$t_{pd}$  (DATA) = 2.5 ns TYP.  
 $t_{pd}$  (CLOCK) = 3.0 ns TYP.

10131  
DUAL TYPE D MASTER-SLAVE FLIP FLOP



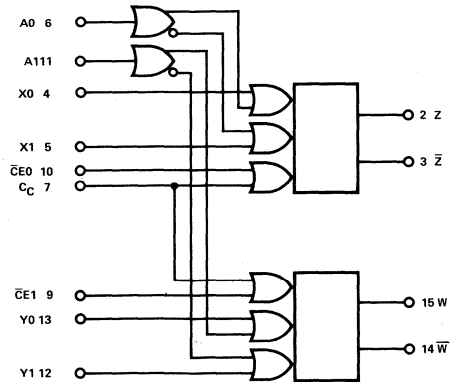
f = 170 MHz TYP.

10132  
DUAL MULTIPLEXER-LATCH  
(WITH RESET)



$t_{pd}$  (DATA) = 2.5 ns TYP.  
 $t_{pd}$  (CLOCK) = 4.0 ns TYP.

10134  
DUAL MULTIPLEXER-LATCH

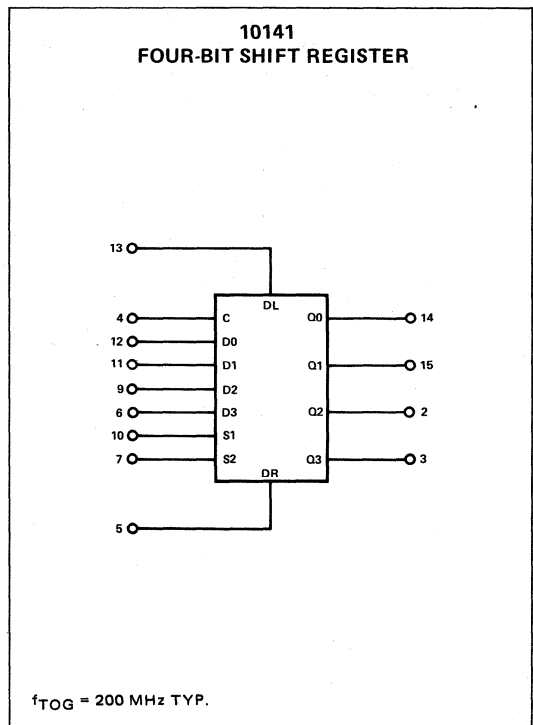
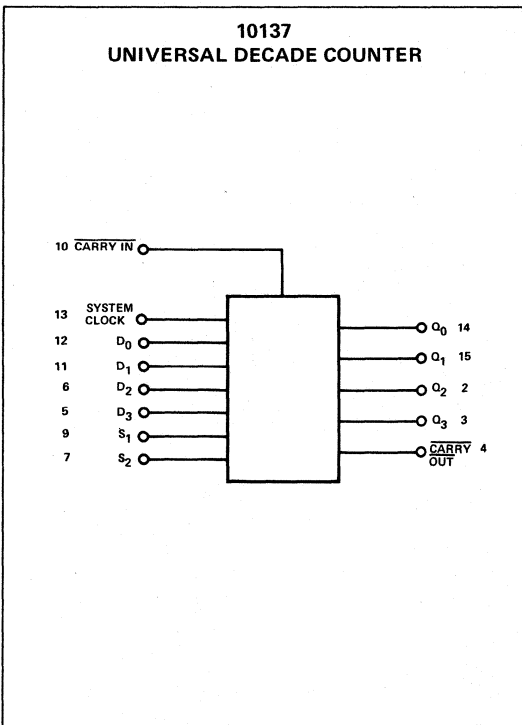
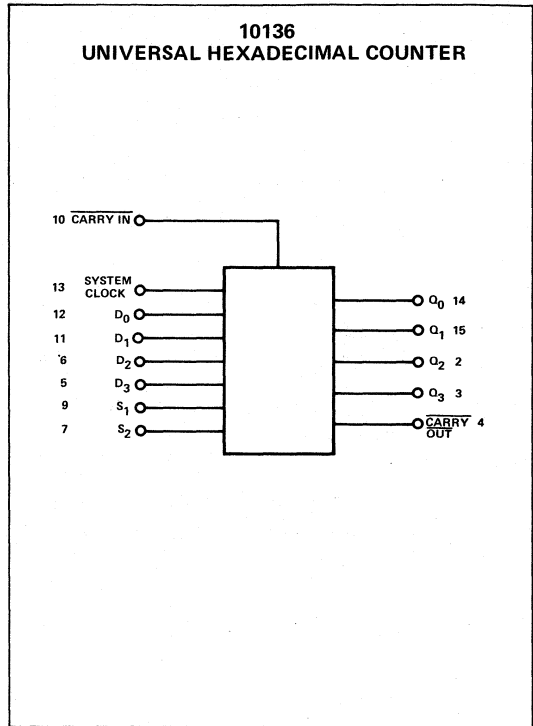
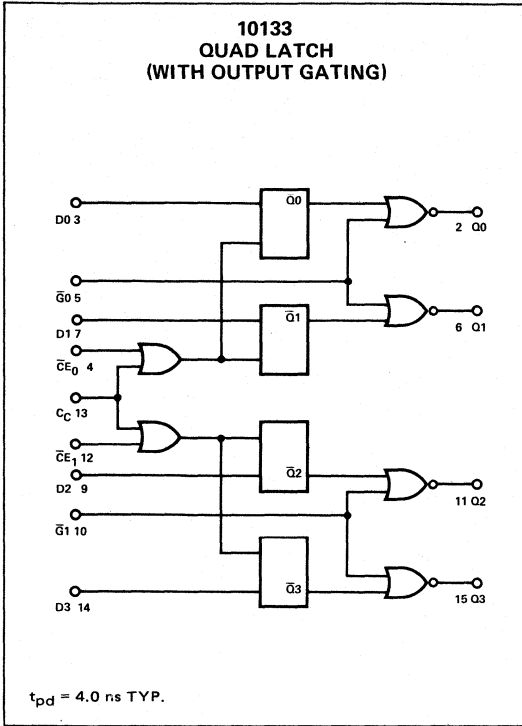


$t_{pd}$  (DATA) = 2.5 ns TYP.  
 $t_{pd}$  (CLOCK) = 4.0 ns TYP.

NOTES:  $V_{CC1} = 1$ ,  $V_{CC2} = 16$ ,  $V_{EE} = 8$

POSITIVE LOGIC: HIGH LEVEL = '1'

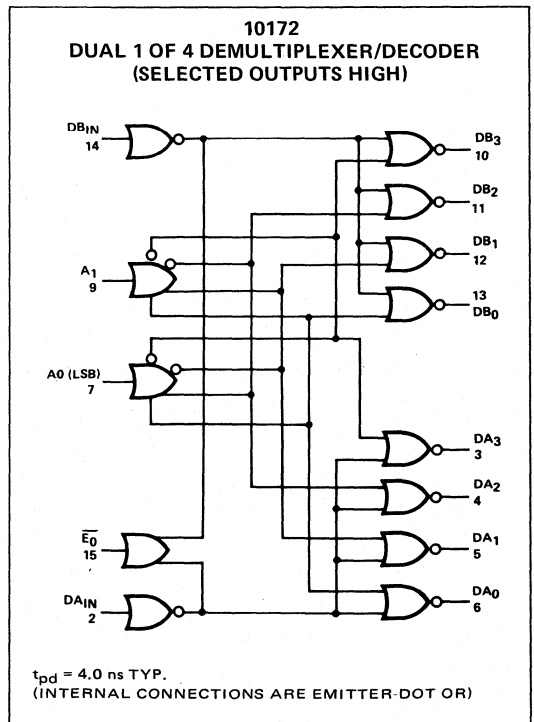
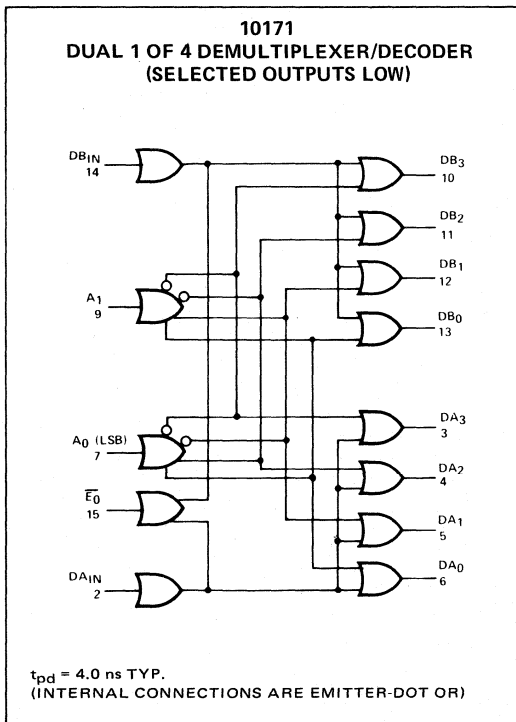
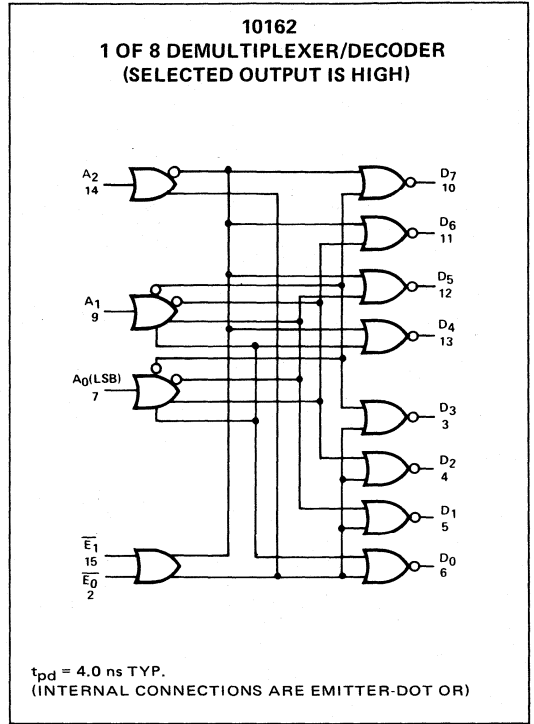
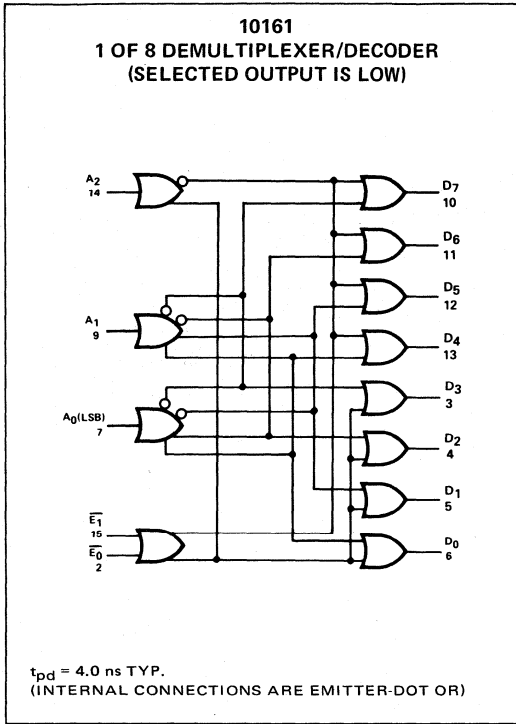
LOGIC DIAGRAMS: MSI: QUAD LATCH, COUNTERS, SHIFT REGISTER



NOTES:  $V_{CC1} = 1, V_{CC2} = 16, V_{EE} = 8$

POSITIVE LOGIC: HIGH LEVEL = '1'

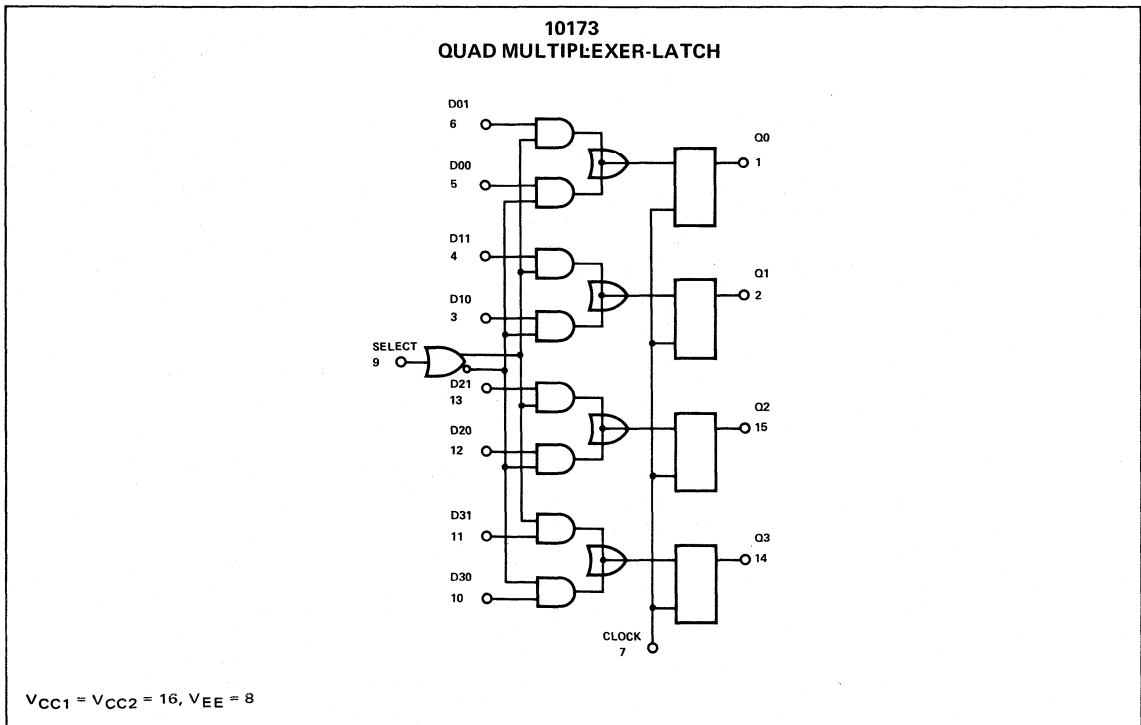
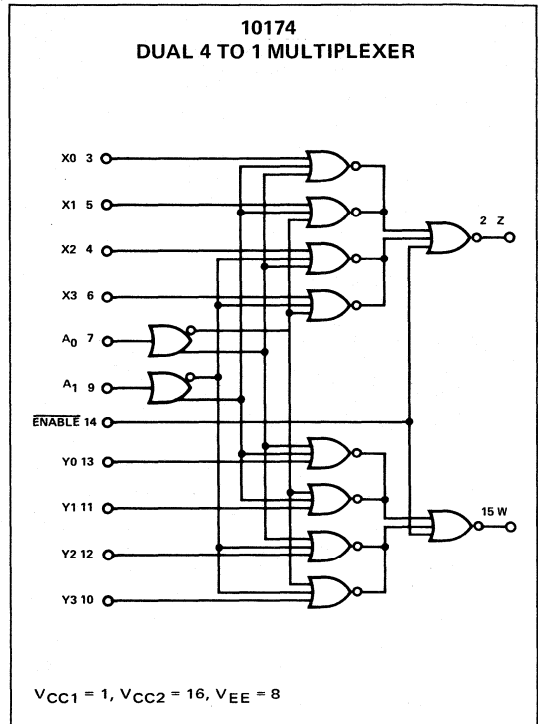
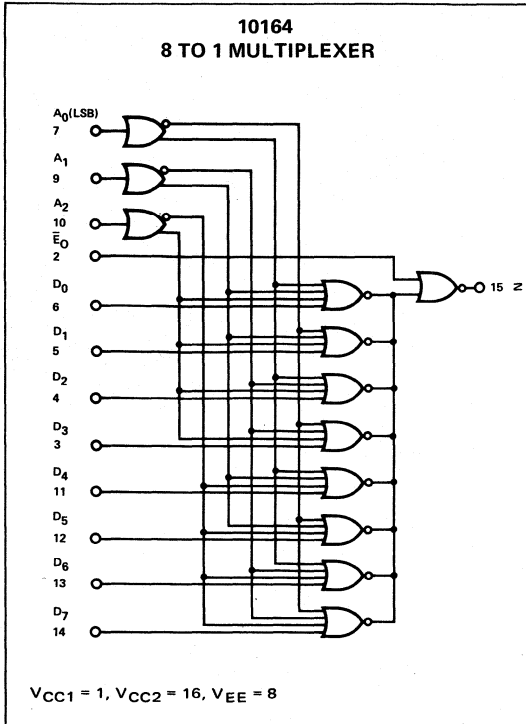
LOGIC DIAGRAMS: MSI DECODERS



NOTES:  $V_{CC1} = 1$ ,  $V_{CC2} = 16$ ,  $V_{EE} = 8$

POSITIVE LOGIC: HIGH LEVEL = '1'

LOGIC DIAGRAMS: MSI: MULTIPLEXERS, QUAD MULTIPLEXER-LATCH

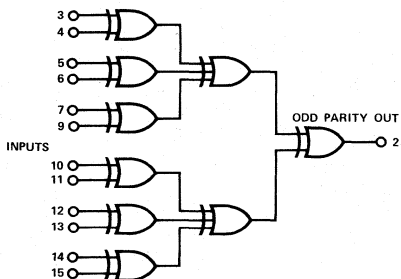


NOTE: POSITIVE LOGIC: HIGH LEVEL = '1'

LOGIC DIAGRAMS: MSI: PARITY AND ALU FUNCTIONS

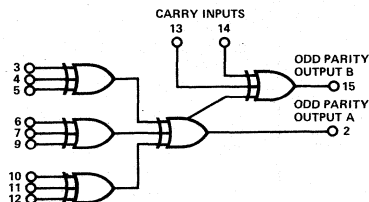
TO BE ANNOUNCED

10160  
12-BIT PARITY CIRCUIT



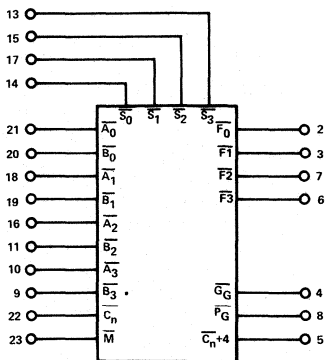
$V_{CC1} = 1, V_{CC2} = 16, V_{EE} = 8$

10170  
9 + 2 PARITY CIRCUIT



$t_{pd}$  (OUTPUT A) = 4.0 ns TYP.  
 $t_{pd}$  (OUTPUT B) = 6.0 ns TYP.  
 $V_{CC1} = 1, V_{CC2} = 16, V_{EE} = 8$

10181  
4-BIT ARITHMETIC UNIT (16 ARITHMETIC FUNCTIONS AND 16 LOGICAL OPERATIONS)



$t_{pd} = 7.0ns (\overline{A1} \text{ TO } \overline{F})$   
 $t_{pd} = 5.0 ns (\overline{A1} \text{ TO } \overline{Cn} + 4)$   
 $V_{CC1} = 1, V_{CC2} = 24, V_{EE} = 12$

NOTE: POSITIVE LOGIC: HIGH LEVEL = '1'



10100B, F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10100 is a high speed Quad 3-Input NOR Gate. All inputs are terminated with a 50K ohm resistor to  $V_{EE}$  which eliminates the need to tie unused inputs low. The gate has an excellent speed-power product of 50 picojoules. The 10100 is optimized for high performance logic applications. This gate meets the ECL 10,000 Series standard voltage current and rise and fall time specifications.

Each gate has one input connected to pin 9.

## FEATURES

- FAST PROPAGATION DELAY = 20ns TYP
- COMMON INPUT FOR GATING
- LOW POWER DISSIPATION = 100mW/PACKAGE TYPE (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE 50Ω LINES
- HIGH Z INPUTS – INTERNAL 50kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2V \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

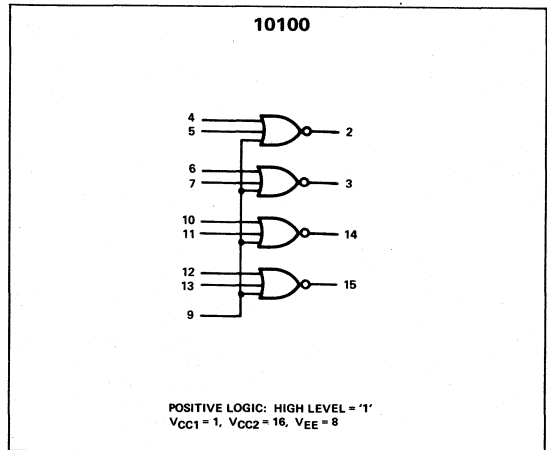
## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

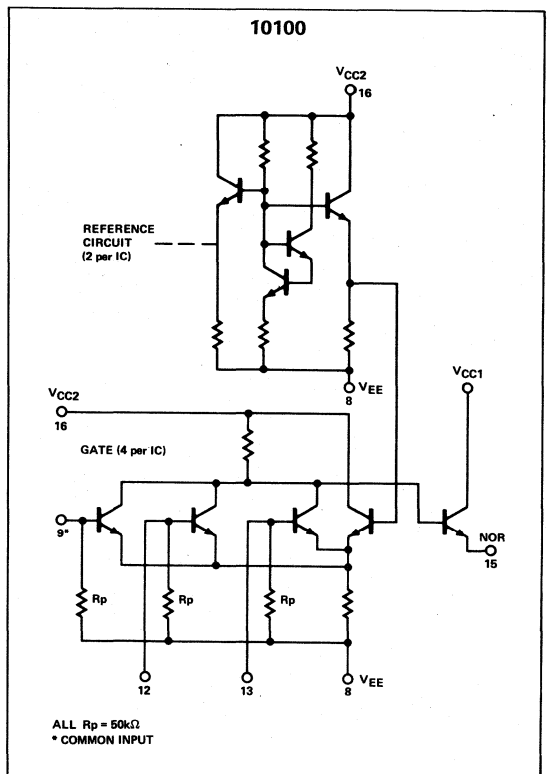
## PACKAGE TYPE

- B: 16 pin Silicone Dip
- F: 16 pin CERDIP

## LOGIC DIAGRAM



## CIRCUIT SCHEMATIC



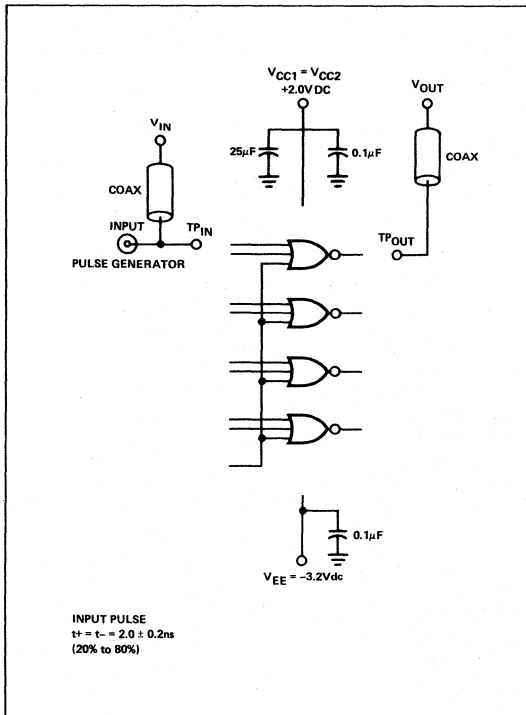
**ELECTRICAL CHARACTERISTICS**

At Listed Voltages and Ambient Temperatures

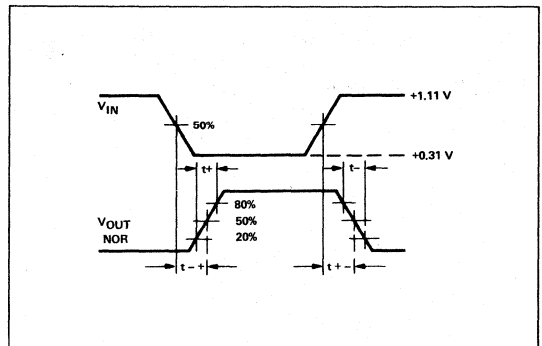
Characteristic	Symbol	Pin Under Test	10100 Test Limits										TEST VOLTAGE VALUES					Gnd
			-30°C		+25°C		+85°C		(Volts)									
			Min	Max	Min	Typ	Max	Min	Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>				
			Unit										V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>	
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	20	26	—	—	—	—	—	—	—	—	8	1.16	
Input Current	I <sub>inH</sub>	4	—	—	—	—	265	—	—	—	—	—	—	—	—	8	1.16	
		9	—	—	—	—	550	—	—	—	—	—	—	—	—	8	1.16	
	I <sub>inL</sub>	4	—	—	0.5	—	—	—	—	—	—	—	—	—	—	8	1.16	
		9	—	—	0.5	—	—	—	—	—	—	—	—	—	—	8	1.16	
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	—	4	—	—	—	8	1.16	
		2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	—	9	—	—	—	8	1.16	
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	9	—	—	—	—	8	1.16	
		2	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	4	—	—	—	—	8	1.16	
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	—	9	—	8	1.16	
		2	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	—	4	—	8	1.16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	9	—	—	—	8	1.16	
		2	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	4	—	—	—	8	1.16	
Switching Times* (50-ohm load)																		
Propagation Delay	t <sub>4+2-</sub> t <sub>4-2+</sub>	2	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	—	—	Pulse In	Pulse Out	-3.2V	+2.0V	8	1.16
		2	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	—	—	4	2	8	8	1.16	
Rise Time (20 to 80%)	t <sub>2+</sub>	2	1.1	3.6	1.1	2.0	3.3	1.1	3.7	ns	—	—	4	2	8	8	1.16	
		2	1.1	3.6	1.1	2.0	3.3	1.1	3.7	ns	—	—	4	2	8	8	1.16	
Fall Time (20 to 80%)	t <sub>2-</sub>	2	1.1	3.6	1.1	2.0	3.3	1.1	3.7	ns	—	—	4	2	8	8	1.16	
		2	1.1	3.6	1.1	2.0	3.3	1.1	3.7	ns	—	—	4	2	8	8	1.16	

\*Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10101F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10101 is a high speed 2-input OR/NOR quad gate with complementary outputs. The 10101 is particularly useful as a quad differential line driver.

Each gate has one input connected to pin 12. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The gate has an excellent speed-power product of 50 picojoules. The 10101 is optimized for high performance logic applications. This gate meets the ECL 10,000 Series standard voltage, current and rise and fall time specifications.

## FEATURES

- FAST PROPAGATION DELAY = 20 ns TYP
- COMPLEMENTARY OR/NOR OUTPUTS  
– EXCELLENT FOR DRIVING TWISTED PAIRS
- COMMON INPUT FOR GATING
- LOW POWER DISSIPATION = 100 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
– CAN DRIVE 50 ohm LINES
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

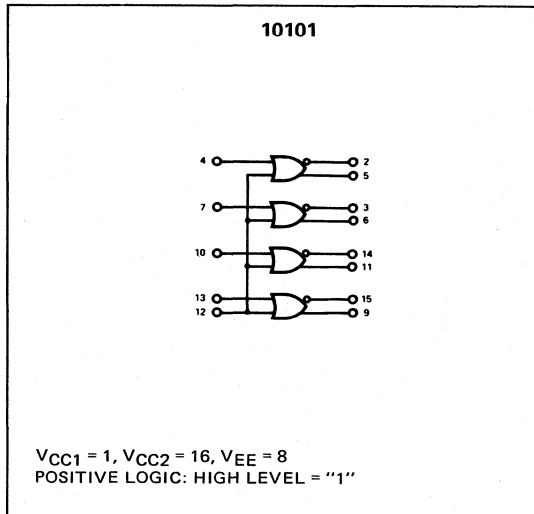
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

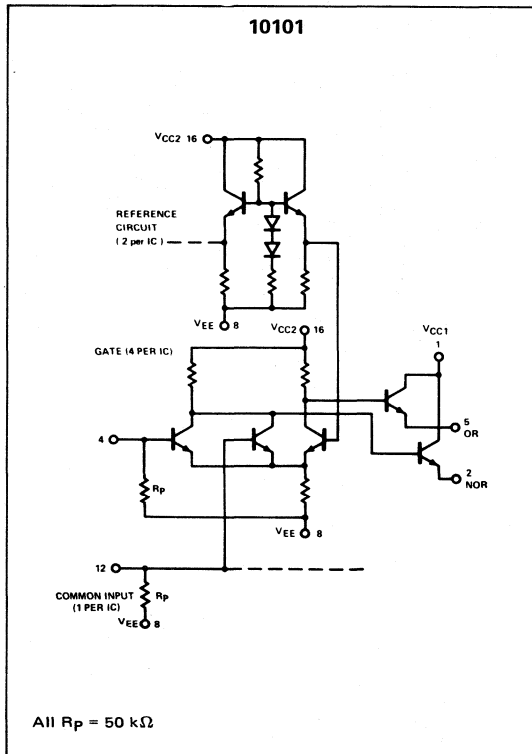
## PACKAGE TYPE

- F: 16 Pin CERDIP

## LOGIC DIAGRAM



## CIRCUIT SCHEMATIC

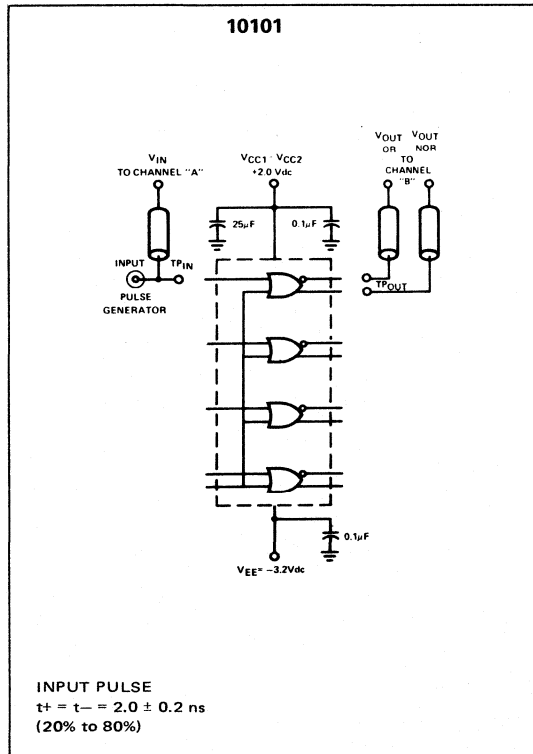


**ELECTRICAL CHARACTERISTICS**  
(at Listed Voltages and Ambient Temperatures).

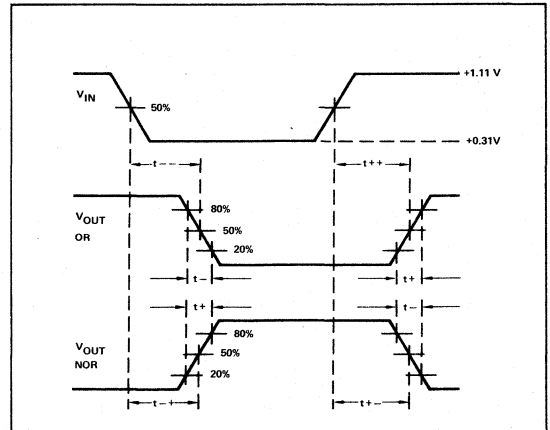
Characteristic	Symbol	Pin Under Test	10101 Test Limits						TEST VOLTAGE VALUES					Unit	V <sub>CC</sub> Gnd	
			-30°C		+25°C		+85°C		(Volts)							
			Min	Max	Min	Max	Min	Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	VEE			
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	20	26	-	-	-	-	-	-	-	8	1,16
Input Current	I <sub>inH</sub>	4	-	-	-	265	-	-	-	-	-	-	-	-	8	1,16
		12	-	-	-	550	-	-	-	-	-	-	-	-	8	1,16
	I <sub>inL</sub>	4	-	-	0.5	-	-	-	-	-	-	4	-	-	8	1,16
		12	-	-	0.5	-	-	-	-	-	-	12	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	5	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	12	-	-	-	8	1,16
		5	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	4	-	-	-	8	1,16
		2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	-	12	-	-	8	1,16
		2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	-	4	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	5	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	12	-	-	8	1,16
		5	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	4	-	-	8	1,16
		2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	12	-	-	-	8	1,16
		2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	4	-	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	5	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	12	-	-	8	1,16
		5	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	4	-	-	8	1,16
		2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	12	-	8	1,16
		2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	4	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	5	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	-	12	-	8	1,16
		5	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	-	4	-	8	1,16
		2	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	12	-	-	8	1,16
		2	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	4	-	-	8	1,16
Switching Times * (50-ohm load)																
Propagation Delay	t <sub>4+2-</sub>	2	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	-	-	4	2	8	1,16
	t <sub>4-2+</sub>	2	↓	↓	↓	↓	↓	↓	↓	↓	-	-	2	2	8	1,16
	t <sub>4+5+</sub>	5	↓	↓	↓	↓	↓	↓	↓	↓	-	-	5	5	8	1,16
	t <sub>4-5-</sub>	5	↓	↓	↓	↓	↓	↓	↓	↓	-	-	5	5	8	1,16
Rise Time (20% to 80%)	t <sub>2+</sub>	5	1.1	3.6	1.1	3.3	1.1	3.7	↓	↓	-	-	2	2	8	1,16
Fall Time (20% to 80%)	t <sub>2+</sub>	5	↓	↓	↓	↓	↓	↓	↓	↓	-	-	5	5	8	1,16
	t <sub>2-</sub>	5	↓	↓	↓	↓	↓	↓	↓	↓	-	-	2	2	8	1,16

\*Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



- NOTES:
- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
  - For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
  - Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
  - All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10102B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10102 is a high speed quad 2-input NOR gate. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The gate has an excellent speed-power product of 50 picojoules. The 10102 is optimized for high performance logic applications. This gate meets the ECL 10,000 Series standard voltage current and rise and fall time specifications.

## FEATURES

- FAST PROPAGATION DELAY = 2.0 ns TYP
- LOW POWER DISSIPATION = 100 mW/PACKAGE (NO LOAD)
- HIGH FANOUT CAPABILITY  
- CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

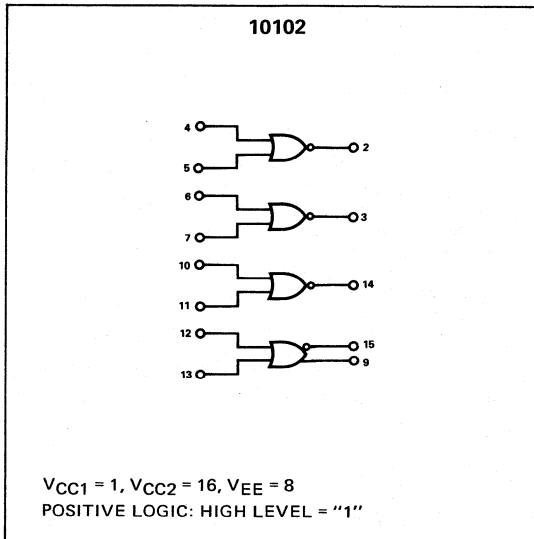
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

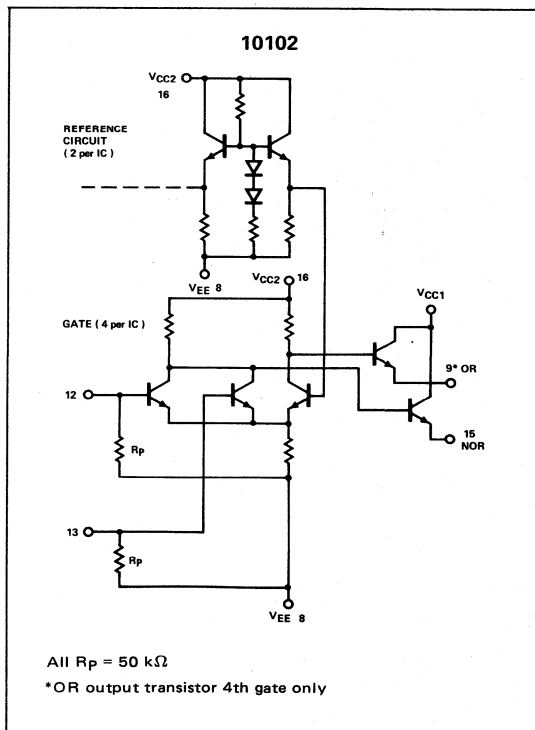
## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

## LOGIC DIAGRAM



## CIRCUIT SCHEMATIC



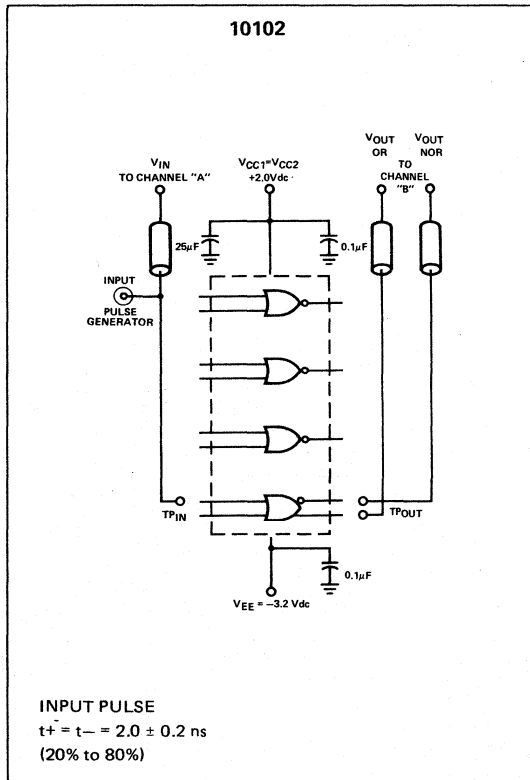
# SIGNETICS QUAD 2-INPUT NOR GATE ■ 10102

## ELECTRICAL CHARACTERISTICS (at Listed Voltages and Ambient Temperatures).

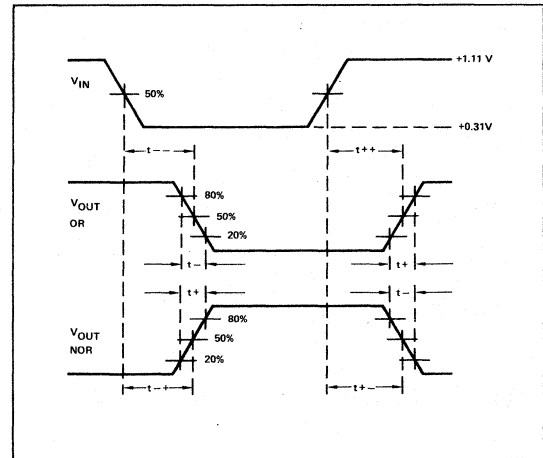
Characteristic	Symbol	Pin Under Test	10102 Test Limits							Unit	TEST VOLTAGE VALUES (Volts)					V <sub>CC</sub> Gnd		
			-30°C		+25°C			+85°C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>			
			Min	Max	Min	Typ	Max	Min	Max									
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	20	26	-	-	mAdc	-	-	-	-	8	1,16		
Input Current	I <sub>IH</sub>	12	-	-	-	-	265	-	-	μAdc	12	-	-	-	8	1,16		
	I <sub>IL</sub>	12	-	-	0.5	-	-	-	-	μAdc	-	12	-	-	8	1,16		
Logic "1" Output Voltage	V <sub>OH</sub>	9	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	V <sub>dcc</sub>	12	-	-	-	8	1,16		
		9	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	V <sub>dcc</sub>	13	-	-	-	8	1,16		
		15	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	V <sub>dcc</sub>	-	12	-	-	8	1,16		
Logic "0" Output Voltage	V <sub>OL</sub>	9	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	V <sub>dcc</sub>	-	13	-	-	8	1,16		
		9	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	V <sub>dcc</sub>	-	12	-	-	8	1,16		
		15	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	V <sub>dcc</sub>	-	13	-	-	8	1,16		
Logic "1" Threshold Voltage	V <sub>OHA</sub>	9	-1.080	-	-0.980	-	-	-0.910	-	V <sub>dcc</sub>	-	12	-	-	8	1,16		
		9	-1.080	-	-0.980	-	-	-0.910	-	V <sub>dcc</sub>	-	13	-	-	8	1,16		
		15	-1.080	-	-0.980	-	-	-0.910	-	V <sub>dcc</sub>	-	12	-	-	8	1,16		
Logic "0" Threshold Voltage	V <sub>OLA</sub>	9	-	-1.655	-	-1.630	-	-1.595	-	V <sub>dcc</sub>	-	-	-	12	8	1,16		
		9	-	-1.655	-	-1.630	-	-1.595	-	V <sub>dcc</sub>	-	-	-	13	8	1,16		
		15	-	-1.655	-	-1.630	-	-1.595	-	V <sub>dcc</sub>	-	12	-	-	8	1,16		
Switching Times* (50-ohm load)	Propagation Delay	t <sub>12+</sub> 15-	15	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	-	-	-	-	-	-	
		t <sub>12-</sub> 15+	15	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-	
		t <sub>12+</sub> 9+	9	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-	
		t <sub>12-</sub> 9-	9	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-	
		t <sub>15+</sub>	15	1.1	3.6	1.1	2.0	3.3	1.1	3.7	ns	-	-	-	-	-	-	
Rise Time (20% to 80%)	t <sub>9+</sub>	9	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-		
	t <sub>9-</sub>	9	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-		
Fall Time (20% to 90%)	t <sub>15-</sub>	15	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-		
	t <sub>9-</sub>	9	↓	↓	↓	↓	↓	↓	↓	↓	-	-	-	-	-	-		
											Pulse In		Pulse Out		-3.2 V		+2.0 V	

\*Unused outputs connected to a 50-ohm resistor to ground.

## SWITCHING TIME TEST CIRCUIT



## PROPAGATION DELAY WAVEFORMS @ 25°C



### NOTES:

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>IN</sub> to input pin and TP<sub>OUT</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10105B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10105 package contains one 3 input OR/NOR gate, and two 2 input OR/NOR gates. The 10105 is optimized for high performance logic applications. Each gate has an excellent speed power product of 50 picojoules. All inputs are terminated with a 50 kΩ resistor to VEE which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout is ideal for a transmission line environment. This gate meets the ECL 10,000 Series standard voltage, current, and rise and fall time specifications.

Complementary outputs make the 10105 particularly useful for differential line driving.

## FEATURES

- FAST PROPAGATION DELAY = 2.0 ns TYP
- POWER DISSIPATION = 75 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY  
- CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: VEE = -5.2 V ±5% RECOMMENDED
- COMPLEMENTARY OR/NOR OUTPUTS
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

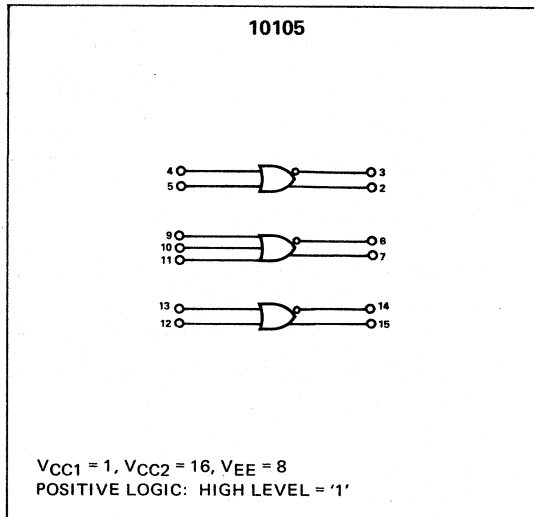
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

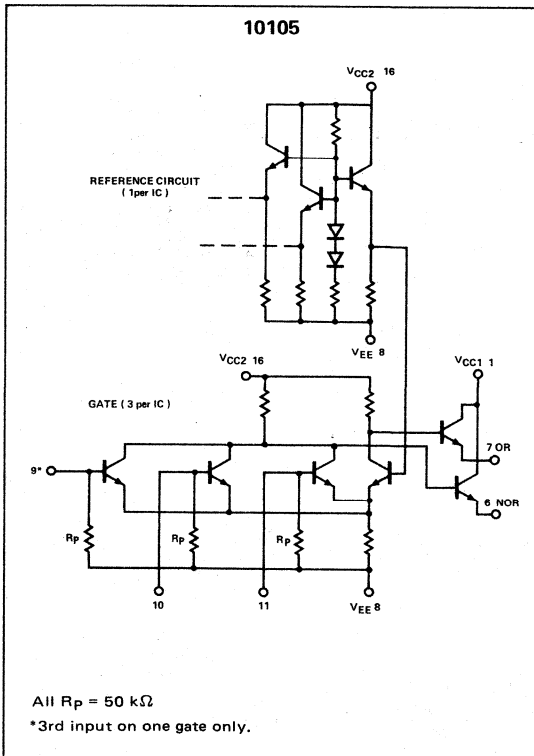
## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

## LOGIC DIAGRAM



## CIRCUIT SCHEMATIC



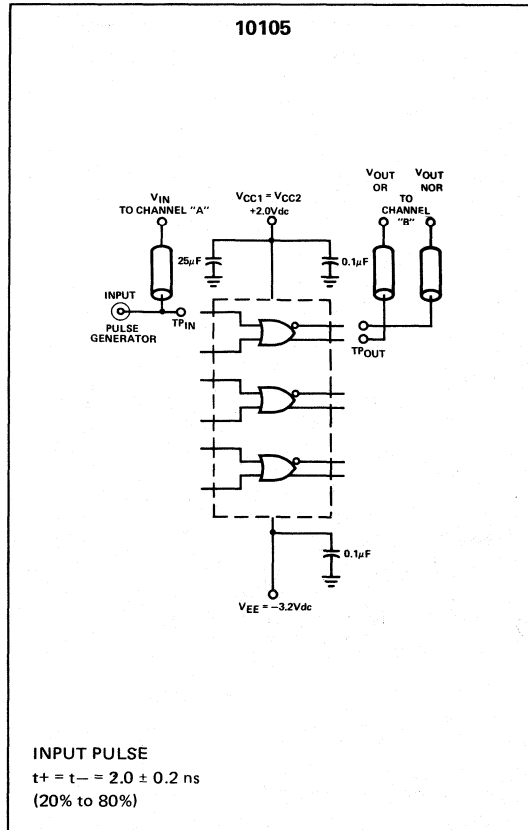
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

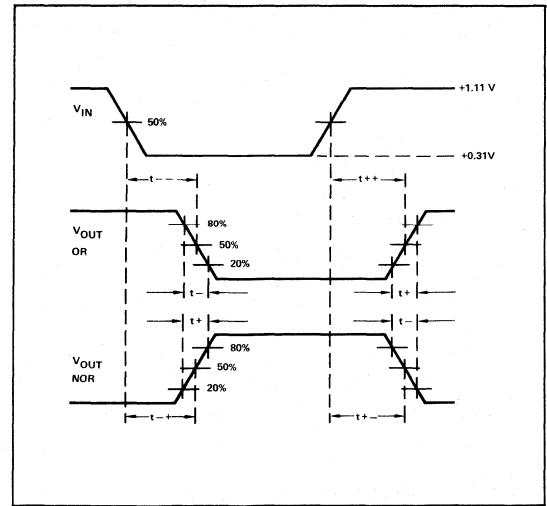
Characteristic	Symbol	Pin Under Test	10105 Test Limits										TEST VOLTAGE VALUES					(V <sub>CC</sub> ) Gnd
			-30° C			+25° C			+85° C			(Volts)						
			Min	Max	Typ	Min	Max	Min	Max	Min	Max	Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>	
			TEST VOLTAGE APPLIED TO PINS LISTED BELOW:															
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	15	21	—	—	—	mAdc	—	—	—	—	8	1,16	
Input Current	I <sub>inH</sub>	4	—	—	—	—	265	—	—	—	μAdc	4	—	—	—	8	1,16	
	I <sub>inL</sub>	4	—	—	0.5	—	—	—	—	—	μAdc	—	4	—	—	8	1,16	
Logic "1" Output Voltage	V <sub>OH</sub>	3	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	—	Vdc	4	—	—	—	8	1,16	
		2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	—	Vdc	4	—	—	—	8	1,16	
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	—	-1.660	-1.825	-1.615	—	Vdc	4	—	—	—	8	1,16	
		2	-1.890	-1.675	-1.850	—	-1.660	-1.825	-1.615	—	Vdc	—	4	—	—	8	1,16	
Logic "1" Threshold Voltage	V <sub>OHA</sub>	3	-1.080	—	-0.980	—	—	-0.910	—	—	Vdc	—	—	—	4	8	1,16	
		2	-1.080	—	-0.980	—	—	-0.910	—	—	Vdc	—	—	—	4	8	1,16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	3	—	-1.655	—	—	-1.630	—	-1.595	—	Vdc	—	—	—	4	8	1,16	
		2	—	-1.655	—	—	-1.630	—	-1.595	—	Vdc	—	—	—	4	8	1,16	
Switching Times * (50-ohm load)																		
Propagation Delay	14+ 3-	3	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	—	—	Pulse In	Pulse Out	-3.2 V	+2.0 V		
	14- 3+	3	↓	↓	↓	↓	↓	↓	↓	↓	—	—	4	3	8	1,16		
	14+ 2+	2	↓	↓	↓	↓	↓	↓	↓	↓	—	—	—	3	—	—		
	14- 2-	2	↓	↓	↓	↓	↓	↓	↓	↓	—	—	—	6	—	—		
Rise Time (20% to 80%)	13+	3	1.1	3.6	1.1	—	3.3	1.1	3.7	—	—	—	—	—	—	—		
	12+	2	↓	↓	↓	↓	↓	↓	↓	↓	—	—	—	—	—	—		
Fall Time (20% to 80%)	13-	3	↓	↓	↓	↓	↓	↓	↓	↓	—	—	—	—	—	—		
	12-	2	↓	↓	↓	↓	↓	↓	↓	↓	—	—	—	—	—	—		

\* Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>IN</sub> to output pin and TP<sub>OUT</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.



10106B,F: -30 to +85°C

## DIGITAL 10,000 SERIES ECL

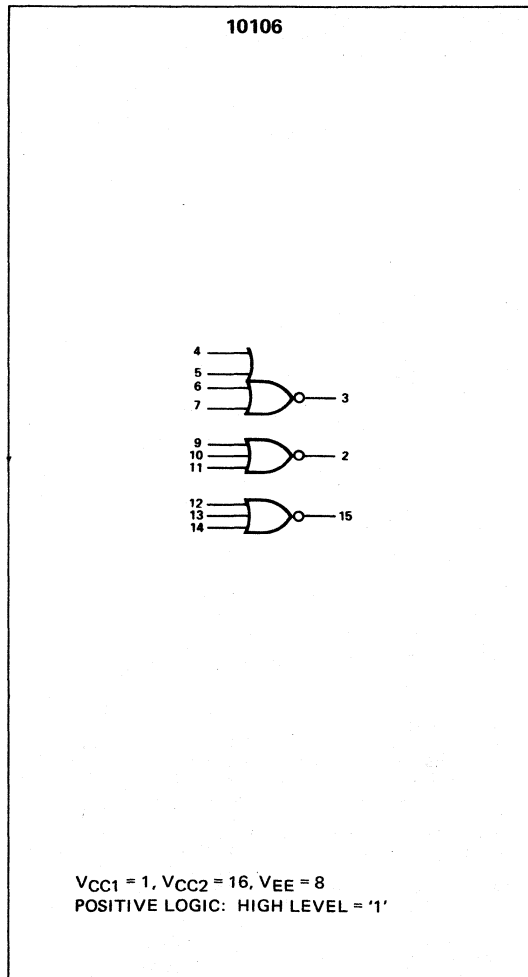
### DESCRIPTION

The 10106 package contains one 4 input NOR gate and two 3 input NOR gates. The 10106 is optimized for high performance logic applications. The gate has an excellent speed power product of 50 picojoules. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout is ideal for a transmission line environment. This gate meets the ECL 10,000 Series standard voltage, current and rise and fall time specifications.

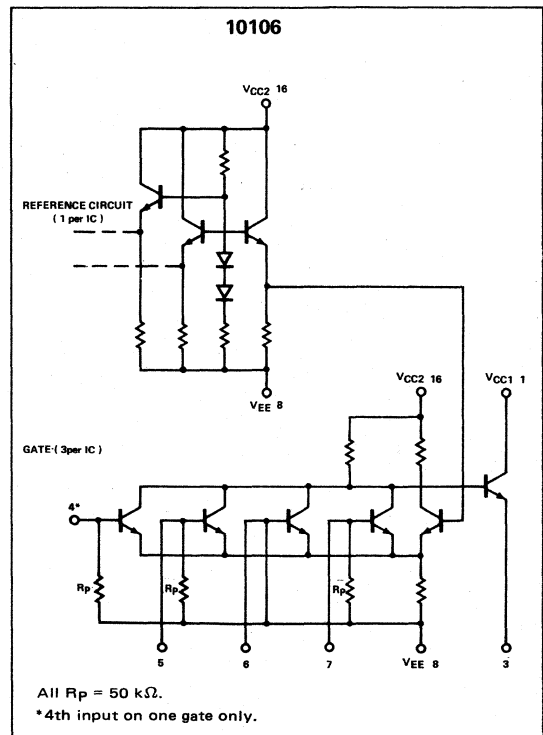
### FEATURES

- FAST PROPAGATION DELAY = 2.0 ns TYP
- LOW POWER DISSIPATION = 75 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY  
– CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

### LOGIC DIAGRAM



### CIRCUIT SCHEMATIC



### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

**ELECTRICAL CHARACTERISTICS**

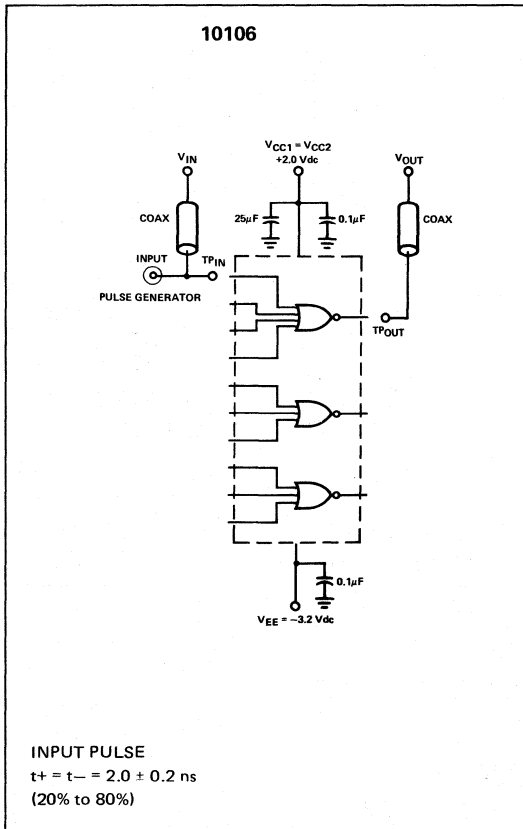
(at Listed Voltages and Ambient Temperatures).

⑥ Test Temperature		TEST VOLTAGE VALUES (Volts)				
		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>
-30° C		-0.890	-1.890	-1.205	-1.500	-5.2
+25° C		-0.810	-1.850	-1.105	-1.475	-5.2
+85° C		-0.700	-1.825	-1.035	-1.440	-5.2

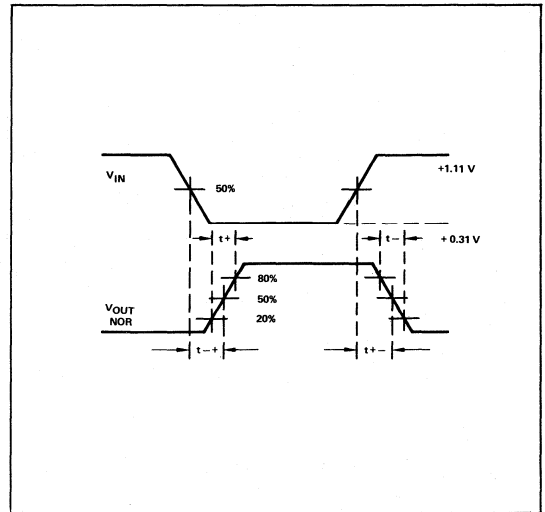
Characteristic	Symbol	Pin Under Test	10106 Test Limits									TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(V <sub>CC</sub> ) Gnd
			-30° C		+25° C			+85° C		Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>		
			Min	Max	Min	Typ	Max	Min	Max								
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	15	21	-	-	-	mAdc	-	-	-	-	8	1,16
Input Current	I <sub>inH</sub>	4	-	-	-	-	265	-	-	-	μAdc	4	-	-	-	8	1,16
	I <sub>inL</sub>	4	-	-	0.5	-	-	-	-	-	μAdc	-	4	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	3	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	-	Vdc	-	4	-	-	8	1,16
		2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	-	Vdc	-	9	-	-	-	-
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	-	-1.660	-1.825	-1.615	-	Vdc	4	-	-	-	8	1,16
		2	-1.890	-1.675	-1.850	-	-1.660	-1.825	-1.615	-	Vdc	9	-	-	-	-	-
Logic "1" Threshold Voltage	V <sub>OHA</sub>	3	-1.080	-	-0.980	-	-	-0.910	-	-	Vdc	-	-	-	4	8	1,16
		2	-1.080	-	-0.980	-	-	-0.910	-	-	Vdc	-	-	-	9	-	-
Logic "0" Threshold Voltage	V <sub>OLA</sub>	3	-	-1.655	-	-	-1.630	-	-1.595	-	Vdc	-	-	4	-	8	1,16
		2	-	-1.655	-	-	-1.630	-	-1.595	-	Vdc	-	-	9	-	-	-
Switching Times * (50-ohm load)																	
Propagation Delay	t <sub>4+ 3-</sub>	3	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	-	-	4	3	8	1,16	
	t <sub>4- 3+</sub>		1.0	3.1	1.0		2.9	1.0	3.3		-	-					
Rise Time (20% to 80%)	t <sub>3+</sub>		1.1	3.6	1.1		3.3	1.1	3.7		-	-					
Fall Time (20% to 80%)	t <sub>3-</sub>		1.1	3.6	1.1		3.3	1.1	3.7		-	-					

\* Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25° C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10107B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

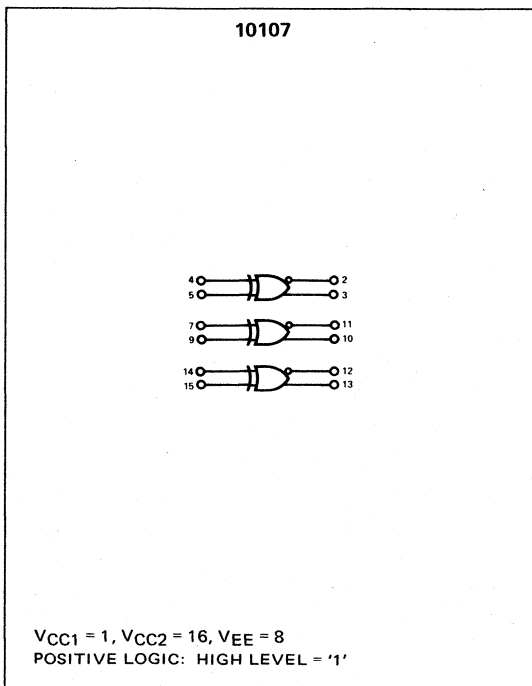
## DESCRIPTION

The 10107 is a triple high speed 2-input Exclusive OR/Exclusive NOR gate. The 10107 is optimized for high speed comparator and parity functions, and has an excellent speed power product for this function. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout are ideal for a transmission line environment. The 10107 contains a temperature tracking internal bias which insures that the threshold point remains in the center of the transition region over temperature. The 10107 has complementary outputs.

## FEATURES

- FAST PROPAGATION DELAY
  - 2.0 ns TYP (INPUTS 4, 9, 14)
  - 2.8 ns TYP (INPUTS 5, 7, 15)
- LOW POWER DISSIPATION = 115 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY
  - CAN DRIVE SIX 50 Ω LINES
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- COMPLEMENTARY OR/NOR OUTPUTS
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

## LOGIC DIAGRAM



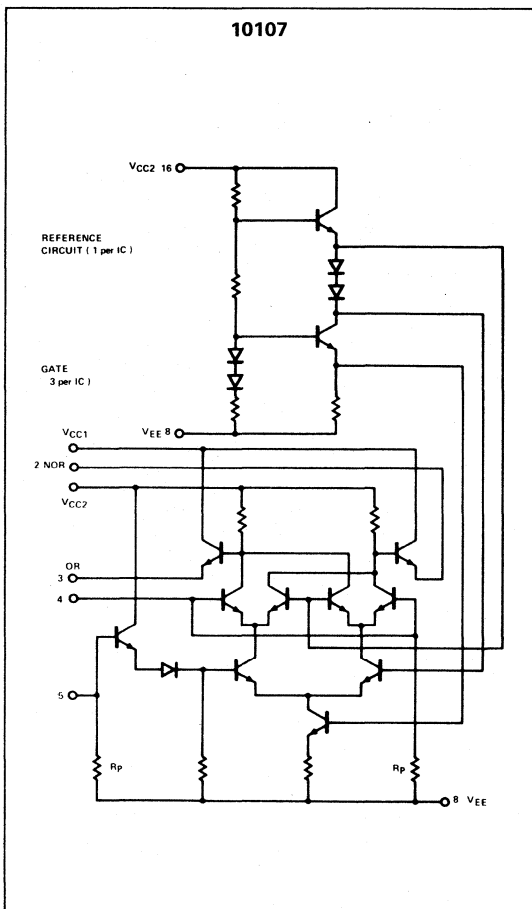
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

## CIRCUIT SCHEMATIC



**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

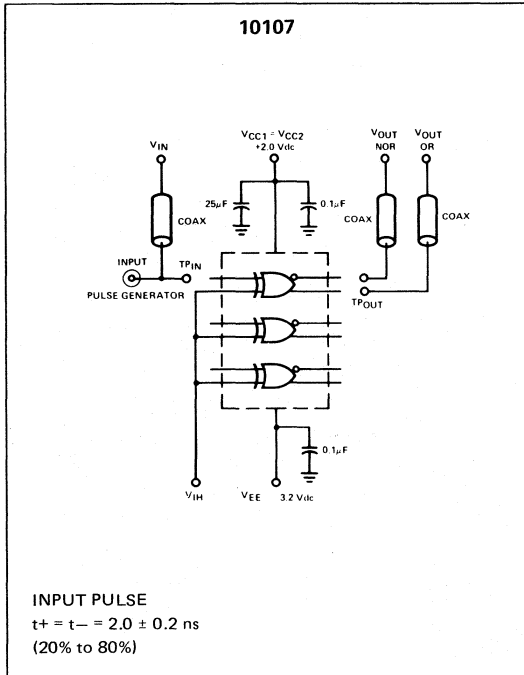
Characteristic	Symbol	Pin Under Test	10107 Test Limits									TEST VOLTAGE VALUES (Volts)					$(V_{CC}/Gnd)$
			-30° C			+25° C			+85° C			$V_{IH}$ max	$V_{IL}$ min	$V_{IHA}$ min	$V_{ILA}$ max	$V_{EE}$	
			Min	Max	Unit	Min	Max	Unit	Min	Max	Unit	-0.890	-1.890	-1.205	-1.500	-5.2	
			Min	Max	Unit	Min	Max	Unit	Min	Max	Unit	-0.810	-1.850	-1.105	-1.475	-5.2	
Power Supply Drain Current	$I_E$	8	-	-	-	28	-	-	-	mAdc	All Inputs	-	-	-	-	8	1,16
	$I_{inH}$	4,9,14	-	-	-	265	-	-	-	$\mu$ Adc	*	-	-	-	-	8	1,16
	$I_{inH}$	5,7,15	-	-	-	220	-	-	-	$\mu$ Adc	*	-	-	-	-	8	1,16
	$I_{inL}$	*	-	-	0.5	-	-	-	-	$\mu$ Adc	*	-	-	-	-	8	1,16
Logic "1" Output Voltage	$V_{OH}$	2	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	-	Vdc	4,5	-	-	-	-	8	1,16
		2	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	-	Vdc	4,5	4,5	-	-	-	8	1,16
		3	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	-	Vdc	4	5	-	-	-	8	1,16
		3	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	-	Vdc	5	4	-	-	-	8	1,16
		3	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	-	Vdc	5	4	-	-	-	8	1,16
Logic "0" Output Voltage	$V_{OL}$	2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	-	Vdc	4	5	-	-	-	8	1,16
		2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	-	Vdc	5	4	-	-	-	8	1,16
		3	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	-	Vdc	4,5	-	-	-	-	8	1,16
		3	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	-	Vdc	5	4	-	-	-	8	1,16
		3	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	-	Vdc	-	4,5	-	-	-	8	1,16
Logic "1" Threshold Voltage	$V_{OHA}$	2	-1.080	-	-0.980	-	-0.910	-	-	Vdc	5	-	4	-	-	8	1,16
		2	-1.080	-	-0.980	-	-0.910	-	-	Vdc	-	-	-	4	-	8	1,16
		3	-1.080	-	-0.980	-	-0.910	-	-	Vdc	-	-	4	-	-	8	1,16
		3	-1.080	-	-0.980	-	-0.910	-	-	Vdc	-	-	5	-	-	8	1,16
Logic "0" Threshold Voltage	$V_{OLA}$	2	-	-1.655	-	-1.630	-	-1.595	-	Vdc	-	-	4	-	-	8	1,16
		2	-	-1.655	-	-1.630	-	-1.595	-	Vdc	-	-	5	-	-	8	1,16
		3	-	-1.655	-	-1.630	-	-1.595	-	Vdc	5	-	4	-	-	8	1,16
		3	-	-1.655	-	-1.630	-	-1.595	-	Vdc	-	-	-	4	-	8	1,16
Switching Times† (50-ohm load)	Propagation Delay	Inputs 4,9, or 14 to either Output	1.0	3.8	Min	Typ	Max	1.1	4.0	ns	5,7,15	-	Pulse In	Pulse Out	-3.2 V	+2.0 V	
					1.1	2.0	3.7										4,9, or 14
Rise Time (20% to 80%)	Fall Time (20% to 80%)	Inputs 5,7, or 15 to either Output	1.1	3.5	Min	Typ	Max	2.5	3.8	ns	4,9,14	-	Any Input	Any Input	Corresponding Ex-OR/Ex-NOR Outputs	-	-
					1.1	2.5	3.5										

\* Individually test each input applying  $V_{IH}$  or  $V_{IL}$  to input under test.

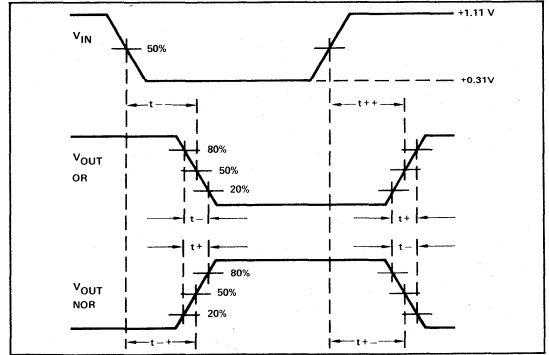
\*\* Any Output

† Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from  $TP_{in}$  to input pin and  $TP_{out}$  to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referred are left electrically open.

10109B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

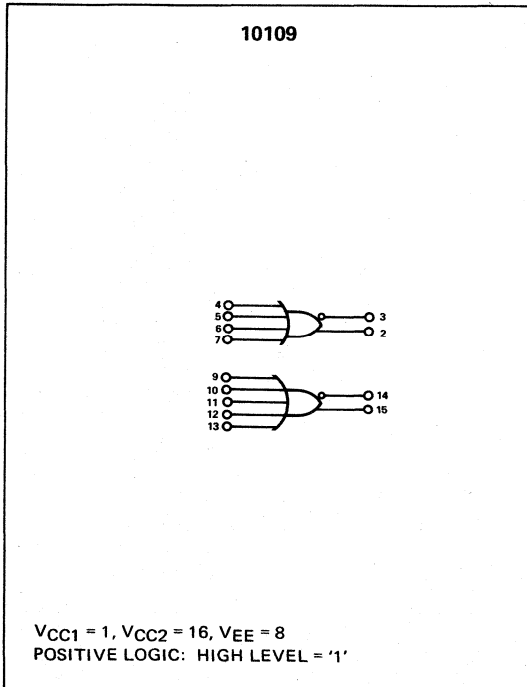
## DESCRIPTION

The 10109 is a high speed 4-input OR/NOR and 5-input OR/NOR dual gate. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The gate has an excellent speed-power product of 50 picojoules. The 10109 is optimized for high performance logic applications. The 10109 has complementary outputs.

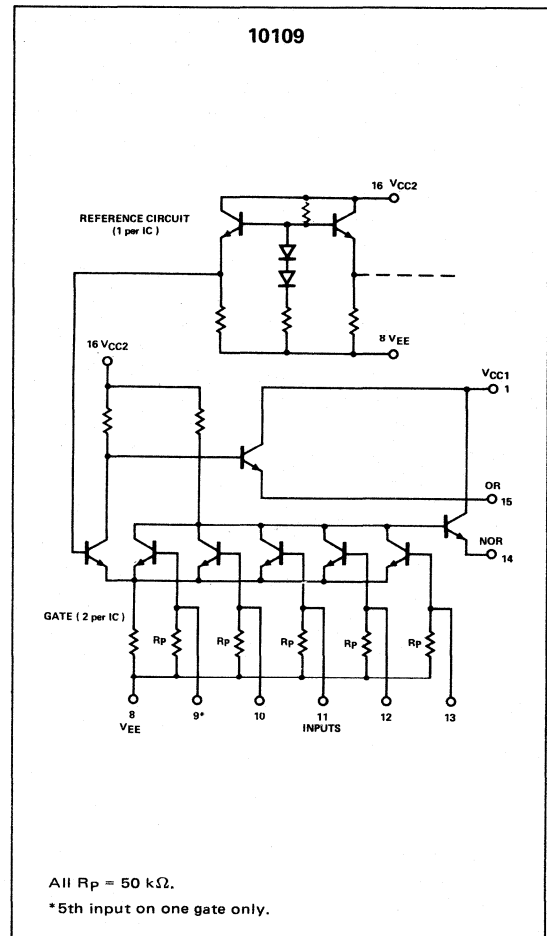
## FEATURES

- FAST PROPAGATION DELAY = 2.0 ns TYP
- LOW POWER DISSIPATION = 50 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
— CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS — INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- COMPLEMENTARY OR/NOR OUTPUTS
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

## LOGIC DIAGRAM



## CIRCUIT SCHEMATIC



## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

**ELECTRICAL CHARACTERISTICS**

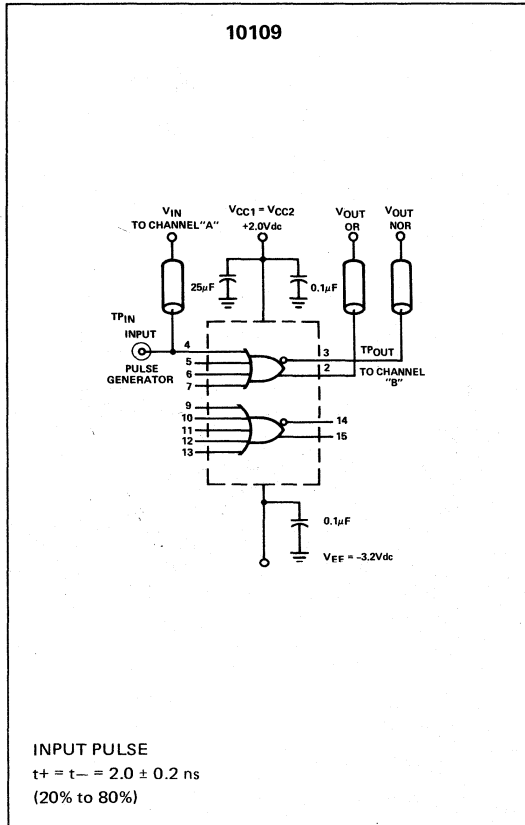
(at Listed Voltages and Ambient Temperatures).

TEST VOLTAGE VALUES				
(Volts)				
Temperature	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max
-30°C	-0.890	-1.890	-1.205	-1.500
+25°C	-0.810	-1.850	-1.105	-1.475
+85°C	-0.700	-1.825	-1.035	-1.440

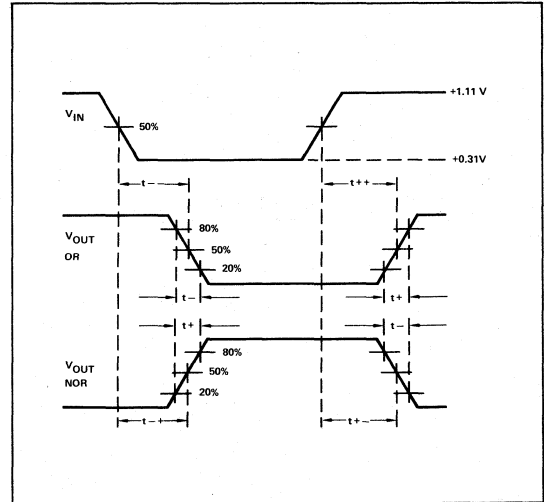
Characteristic	Symbol	Pin Under Test	10109 Test Limits									TEST VOLTAGE APPLIED TO PINS BELOW:					(V <sub>CC</sub> ) Gnd	
			-30°C			+25°C			+85°C			Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max		V <sub>EE</sub>
			Min	Max	Typ	Min	Max	Min	Max									
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	10	14	-	-	-	mAdc	-	-	-	-	8	1,16	
Input Current	I <sub>inH</sub>	4	-	-	-	-	285	-	-	-	μAdc	4	-	-	-	8	1,16	
	I <sub>inL</sub>	4	-	-	0.5	-	-	-	-	-	μAdc	-	4	-	-	8	1,16	
High Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	-	Vdc	4	-	-	-	8	1,16	
		3	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	-	Vdc	-	4	-	-	8	1,16	
Low Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	-	Vdc	-	4	-	-	8	1,16	
		3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	-	Vdc	4	-	-	-	8	1,16	
High Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	-	Vdc	-	-	4	-	8	1,16	
		3	-1.080	-	-0.980	-	-	-0.910	-	-	Vdc	-	-	-	4	8	1,16	
Low Threshold Voltage	V <sub>OLA</sub>	2	-	-1.655	-	-	-1.630	-	-1.595	-	Vdc	-	-	-	4	8	1,16	
		3	-	-1.655	-	-	-1.630	-	-1.595	-	Vdc	-	-	-	-	4	8	1,16
Switching Times * (50-ohm load)																		
Propagation Delay	14+ 2+	2	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	-	-	-	-	2	8	1,16	
	14- 2-	2									-	-	-	-	2			
	14+ 3-	3									-	-	-	-	3			
	14- 3+	3									-	-	-	-	3			
Rise Time (20% to 80%)	12+	2	1.1	3.6	1.1		3.3	1.1	3.7		-	-	-	-	2			
	13+	2									-	-	-	-	3			
Fall Time (20% to 80%)	12-	2									-	-	-	-	2			
	13-	3									-	-	-	-	3			

\* Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 2 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10110B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10110 is a dual high speed 3-input 3-output OR gate. The 10110 is designed to drive up to three transmission lines simultaneously. The multiple outputs of this device also allow the wire-"OR"-ing of several levels of gating for minimization of gate and package count.

The ability to control three parallel lines from a single point makes the 10110 particularly useful in clock distribution applications where minimum clock skew is desired.

### FEATURES

- FAST PROPAGATION DELAY = 2.4 ns TYP (ALL OUTPUTS LOADED)
- POWER DISSIPATION = 150 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY  
- CAN DRIVE SIX 50 Ω LINES
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

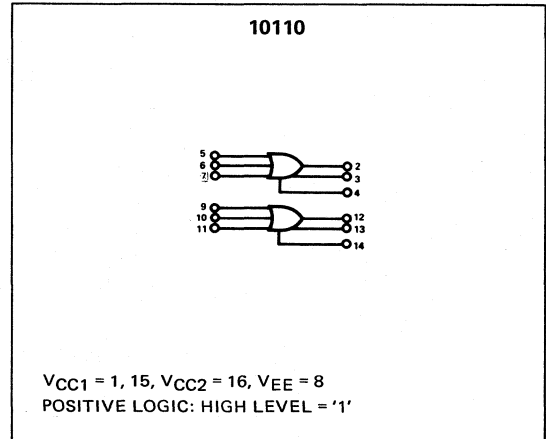
### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

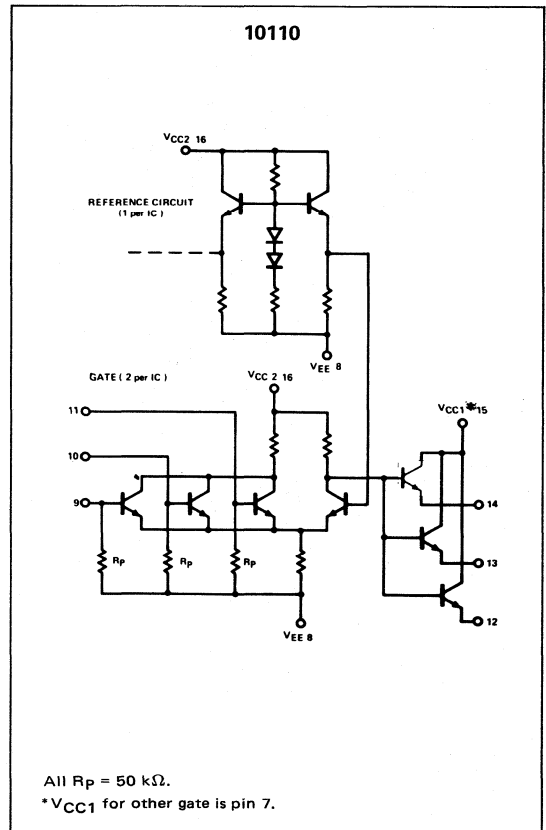
### PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

### LOGIC DIAGRAM



### CIRCUIT SCHEMATIC



# SIGNETICS DUAL 3-INPUT 3-OUTPUT OR GATE ■ 10110

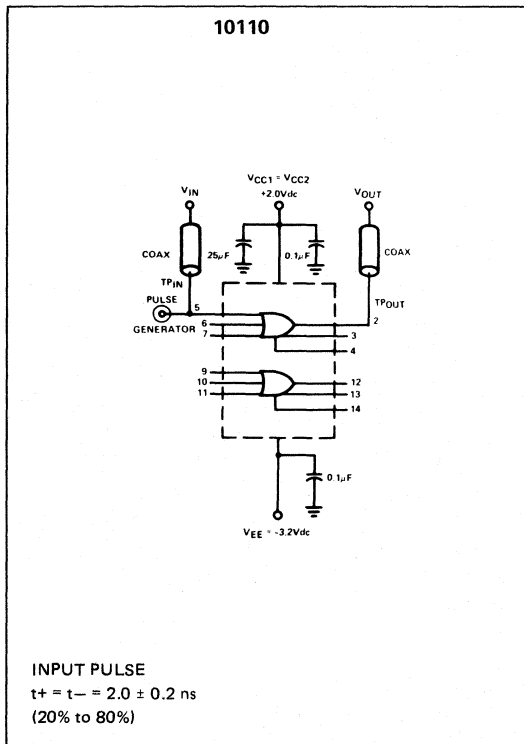
## ELECTRICAL CHARACTERISTICS

(at Listed Voltages and Ambient Temperatures).

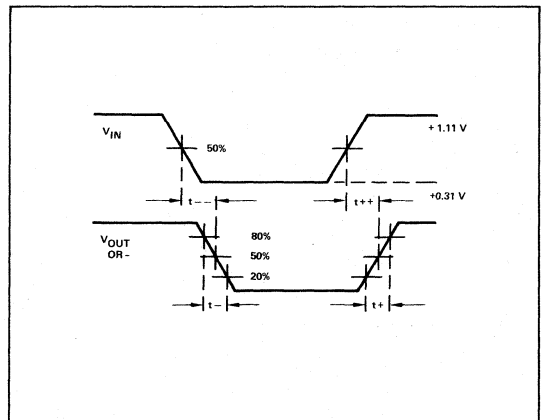
Characteristic	Symbol	Pin Under Test	10110 Test Limits						Unit	TEST VOLTAGE VALUES					(Vcc) Gnd		
			-30°C		+25°C		+85°C			(Volts)							
			Min	Max	Min	Max	Min	Max		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IILA</sub> max	V <sub>EE</sub>			
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	39	—	—	mAdc	—	—	—	—	8	1,15,16		
Input Current	I <sub>inH</sub>	5,6,7	—	—	—	435	—	—	μAdc	—	—	—	—	8	1,15,16		
		I <sub>inL</sub>	5,6,7	—	—	0.5	—	—	—	μAdc	—	—	—	—	8	1,15,16	
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	5	—	—	—	8	1,15,16	
		3	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	6	—	—	—	8	1,15,16	
		4	-1.060	-0.890	-0.960	—	-0.810*	-0.890	-0.700	Vdc	7	—	—	—	8	1,15,16	
Logic "0" Output Voltage	V <sub>OL</sub>	2	—	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	—	5	—	—	8	1,15,16	
		3	—	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	—	6	—	—	8	1,15,16
		4	—	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	—	7	—	—	8	1,15,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	5	—	8	1,15,16	
		3	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	6	—	8	1,15,16	
		4	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	7	—	8	1,15,16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	—	5	8	1,15,16	
		3	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	—	6	8	1,15,16	
		4	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	—	7	8	1,15,16	
Switching Times **																	
Propagation Delay	t <sub>5+2+</sub>	2	1.4	3.5	1.4	2.4	3.5	1.5	3.8	ns	—	—	5	2	8	1,15,16	
	t <sub>5-2-</sub>	2	—	—	—	—	—	—	—	—	—	—	—	2	—	—	
	t <sub>5+3+</sub>	3	—	—	—	—	—	—	—	—	—	—	—	3	—	—	
	t <sub>5-3-</sub>	3	—	—	—	—	—	—	—	—	—	—	—	3	—	—	
	t <sub>5+4+</sub>	4	—	—	—	—	—	—	—	—	—	—	—	4	—	—	
	t <sub>5-4-</sub>	4	—	—	—	—	—	—	—	—	—	—	—	4	—	—	
Rise Time (20% to 80%)	t <sub>2+</sub>	2	1.0	—	1.1	2.2	—	1.2	—	—	—	—	—	2	—	—	
	t <sub>3+</sub>	3	—	—	—	—	—	—	—	—	—	—	—	3	—	—	
	t <sub>4+</sub>	4	—	—	—	—	—	—	—	—	—	—	—	4	—	—	
	t <sub>2-</sub>	2	—	—	—	—	—	—	—	—	—	—	—	2	—	—	
Fall Time (20% to 80%)	t <sub>3-</sub>	3	—	—	—	—	—	—	—	—	—	—	—	3	—	—	
	t <sub>4-</sub>	4	—	—	—	—	—	—	—	—	—	—	—	4	—	—	

\* Individually test each input using the pin connections shown.  
 \*\* Unused outputs connected to a 50-ohm resistor to ground.

## SWITCHING TIME TEST CIRCUIT



## PROPAGATION DELAY WAVEFORMS @ 25°C



- NOTES:
- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
  - For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
  - Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
  - All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.



10111B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

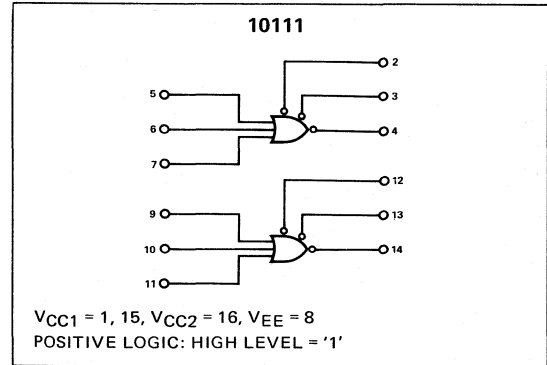
The 10111 is a dual high speed 3-input, 3-output NOR gate. The 10111 is designed to drive up to three transmission lines simultaneously. The multiple outputs of this device also allow the wire-OR-ing of several levels of gating for minimization of gate and package count.

The ability to control three parallel lines from a single point makes the 10111 particularly useful in clock distribution applications where minimum clock skew is desired.

## FEATURES

- FAST PROPAGATION DELAY = 2.4 ns TYP (ALL OUTPUTS LOADED)
- POWER DISSIPATION = 150 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY  
— CAN DRIVE SIX 50 Ω LINES
- HIGH Z INPUTS — INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

## LOGIC DIAGRAM



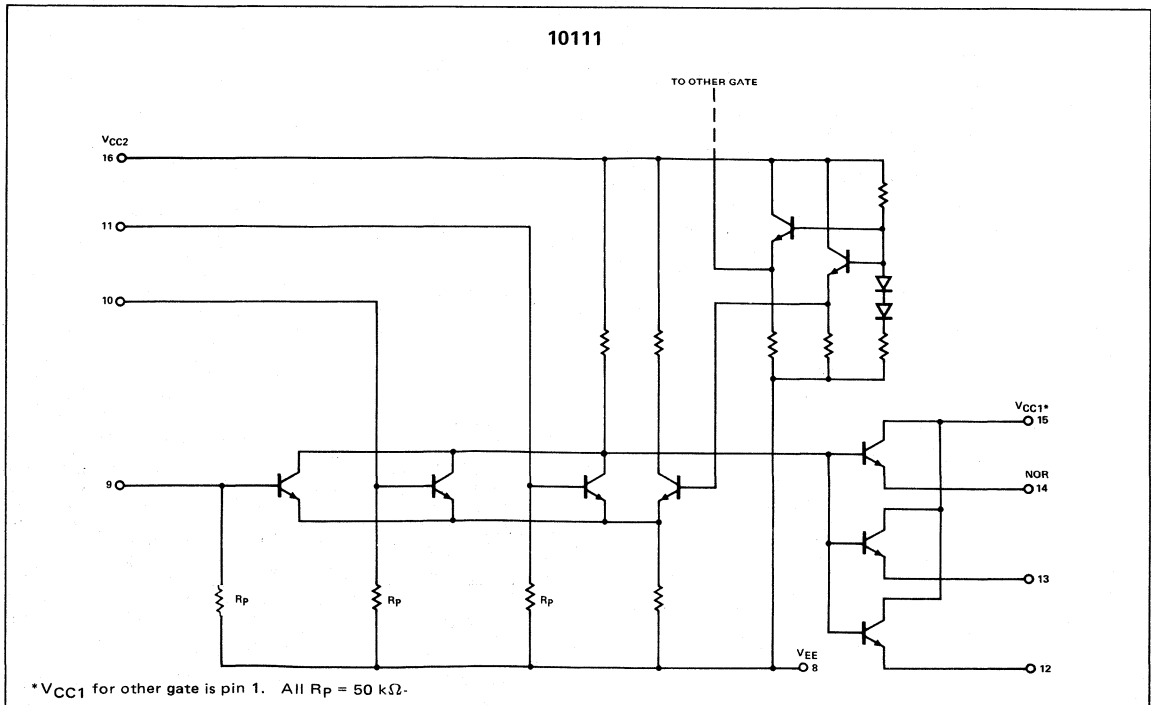
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

## CIRCUIT SCHEMATIC



# SIGNETICS DUAL 3-INPUT 3-OUTPUT NOR GATE ■ 10111

## ELECTRICAL CHARACTERISTICS

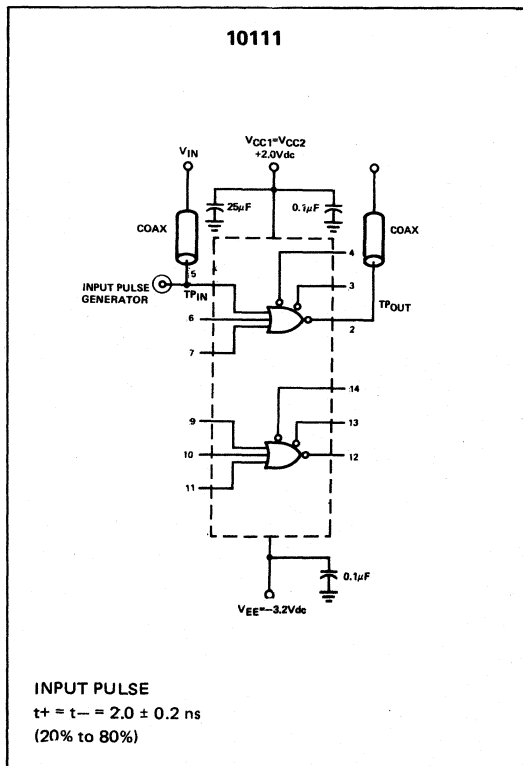
(at Listed Voltages and Ambient Temperatures).

Characteristic	Symbol	Pin Under Test	10111 Test Limits						Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(V <sub>CC</sub> ) Gnd		
			-30°C		+25°C		+85°C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>			
			Min	Max	Min	Typ	Max	Min		Max							
TEST VOLTAGE VALUES (Volts)																	
@ Test Temperature																	
-30°C																	
+25°C																	
+85°C																	
Power Supply Drain Current																	
IE	8						38			mAdc				8	1,15,16		
I <sub>inH</sub>	5,6,7						435			μAdc				8	1,15,16		
I <sub>inL</sub>	5,6,7			0.5						μAdc				8	1,15,16		
Logic "1" Output Voltage																	
VOH	2	-1.060	-0.890	-0.960		-0.810	-0.890	-0.700	Vdc		5			8	1,15,16		
	3	-1.060	-0.890	-0.960		-0.810	-0.890	-0.700	Vdc		6			8	1,15,16		
	4	-1.060	-0.890	-0.960		-0.810	-0.890	-0.700	Vdc		7			8	1,15,16		
Logic "0" Output Voltage																	
VOL	2	-1.890	-1.675	-1.850		-1.650	-1.825	-1.615	Vdc		5			8	1,15,16		
	3	-1.890	-1.675	-1.850		-1.650	-1.825	-1.615	Vdc		6			8	1,15,16		
	4	-1.890	-1.675	-1.850		-1.650	-1.825	-1.615	Vdc		7			8	1,15,16		
Logic "1" Threshold Voltage																	
VOHA	2	-1.080		-0.980			-0.910		Vdc				5	8	1,15,16		
	3	-1.080		-0.980			-0.910		Vdc				6	8	1,15,16		
	4	-1.080		-0.980			-0.910		Vdc				7	8	1,15,16		
Logic "0" Threshold Voltage																	
VOLA	2		-1.655			-1.630		-1.595	Vdc				5	8	1,15,16		
	3		-1.655			-1.630		-1.595	Vdc				6	8	1,15,16		
	4		-1.655			-1.630		-1.595	Vdc				7	8	1,15,16		
Switching Times ** (50-ohm load)																	
Propagation Delay																	
15+ 2-	2	1.4	3.5	1.4	2.4	3.5	1.5	3.8	ns				Pulse In	5	2	8	1,15,16
15- 2+	2												Pulse Out	2	2		
15+ 3-	3													3	3		
15- 3+	3													3	3		
15+ 4-	4													4	4		
15- 4+	4													4	4		
Rise Time (20% to 80%)																	
t <sub>2+</sub>	2	1.0		1.1	2.2	3.5	1.2	3.8						2	2		
t <sub>3+</sub>	3													3	3		
t <sub>4+</sub>	4													4	4		
Fall Time (20% to 80%)																	
t <sub>2-</sub>	2													2	2		
t <sub>3-</sub>	3													3	3		
t <sub>4-</sub>	4													4	4		

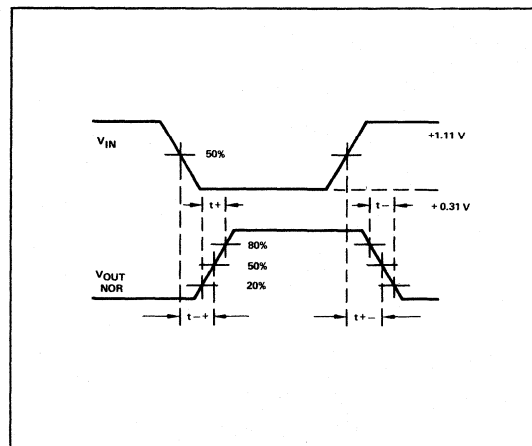
\* Individually test each input using the pin connections shown.

\*\* Unused outputs connected to a 50-ohm resistor to ground.

## SWITCHING TIME TEST CIRCUIT



## PROPAGATION DELAY WAVEFORMS @ 25°C



### NOTES:

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>IN</sub> to input pin and TP<sub>OUT</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10112B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

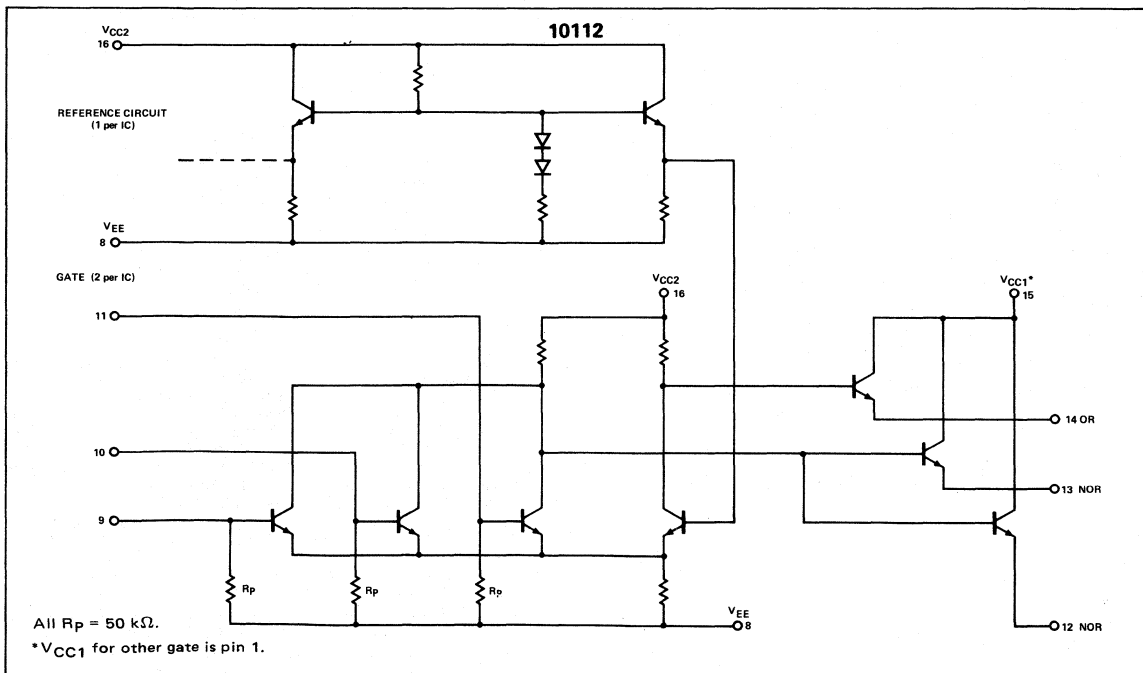
The 10112 is a dual high speed 3-input 1 OR/2 NOR output gate. The 10112 is designed to drive up to three transmission lines simultaneously. The multiple outputs of this device also allow the wire-"OR"-ing of several levels of gating for minimization of gate and package count.

The ability to control three parallel lines from a single point makes the 10112 particularly useful in clock distribution applications where minimum clock skew is desired. The 10112 is suitable for use in memory chip select decoding. The 10112 is particularly useful as a clock amplifier on a board using clock signals of both polarities.

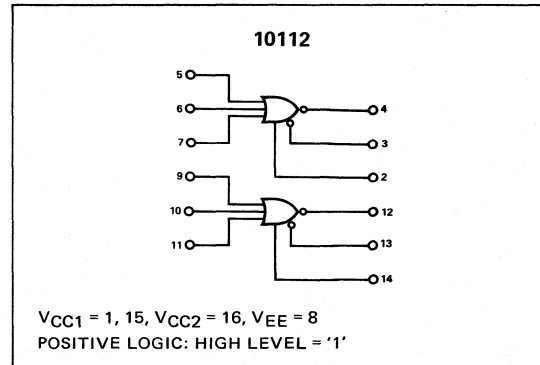
## FEATURES

- FAST PROPAGATION DELAY = 2.4 ns TYP (ALL OUTPUTS LOADED)
- POWER DISSIPATION = 150 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY  
- CAN DRIVE SIX 50 Ω LINES
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

## CIRCUIT SCHEMATIC



## LOGIC DIAGRAM



## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERPDP

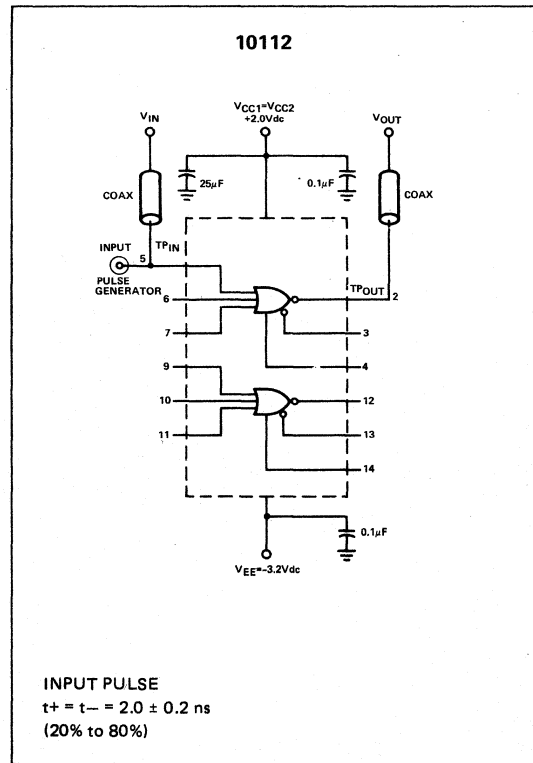
# SIGNETICS DUAL 3-INPUT 1 OR/2 NOR OUTPUT GATE ■ 10112

## ELECTRICAL CHARACTERISTICS

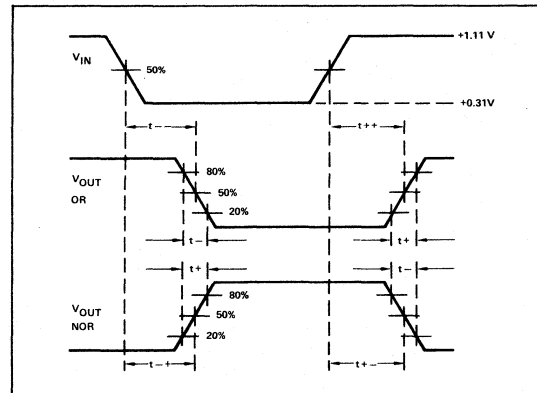
(at Listed Voltages and Ambient Temperatures).

Characteristic	Symbol	Pin Under Test	10112 Test Limits										TEST VOLTAGE APPLIED TO PINS LISTED BELOW				NOTES	
			-30°C		+25°C			+85°C		Unit	TEST VOLTAGE VALUES (Volts)							
			Min	Max	Min	Typ	Max	Min	Max		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max				
			Temperature										V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max		
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	—	38	—	—	—	—	—	—	—	—	5		
Input Current	I <sub>inH</sub>	5	—	—	—	—	420	—	—	—	—	—	—	—	—	5		
	I <sub>inL</sub>	5	—	—	0.5	—	—	—	—	—	—	—	—	—	—	5		
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	5	—	—	—	—	5		
		3	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	—	6	—	—	—	5		
		4	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	—	7	—	—	—	5		
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	—	5	—	—	—	5		
		3	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	6	—	—	—	—	5		
		4	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	7	—	—	—	—	5		
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	5	—	—	5		
		3	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	—	6	—	5		
		4	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	—	—	7	5		
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	—	-1.655	—	—	-1.650	—	-1.595	Vdc	—	—	—	—	5	5		
		3	—	-1.655	—	—	-1.650	—	-1.595	Vdc	—	—	—	—	6	5		
		4	—	-1.655	—	—	-1.650	—	-1.595	Vdc	—	—	—	—	7	5		
Switching Times (50-ohm load) Propagation Delay	t <sub>5+2+</sub> t <sub>5-2-</sub> t <sub>5+3-</sub> t <sub>5-3+</sub>	2	—	—	1.4	2.4	3.5	—	—	ns	—	—	—	—	5	2	2,6	
		2	—	—	—	—	—	—	—	—	—	—	—	—	—	2		
		3	—	—	—	—	—	—	—	—	—	—	—	—	—	3		
		3	—	—	—	—	—	—	—	—	—	—	—	—	—	3		
	t <sub>5+4-</sub> t <sub>5-4+</sub>	4	—	—	—	—	—	—	—	—	—	—	—	—	—	4		
		4	—	—	—	—	—	—	—	—	—	—	—	—	—	4		
		4	—	—	—	—	—	—	—	—	—	—	—	—	—	4		
		4	—	—	—	—	—	—	—	—	—	—	—	—	—	4		
	Rise Time (20% to 80%)	t <sub>2+</sub> t <sub>3+</sub>	2	—	—	1.1	2.2	3.5	—	—	—	—	—	—	—	—		2
			3	—	—	—	—	—	—	—	—	—	—	—	—	—		3
		t <sub>4+</sub>	4	—	—	—	—	—	—	—	—	—	—	—	—	—		4
			4	—	—	—	—	—	—	—	—	—	—	—	—	—		4
	Fall Time (20% to 80%)	t <sub>2-</sub> t <sub>3-</sub>	2	—	—	—	—	—	—	—	—	—	—	—	—	—		2
			3	—	—	—	—	—	—	—	—	—	—	—	—	—		3
t <sub>4-</sub>		3	—	—	—	—	—	—	—	—	—	—	—	—	—	2		
		4	—	—	—	—	—	—	—	—	—	—	—	—	—	3		

### SWITCHING TIME TEST CIRCUIT



### PROPAGATION DELAY WAVEFORMS @ 25°C



- NOTES:
- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
  - For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
  - Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
  - All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
  - Pin 1 = Pin 15 = Pin 16 = V<sub>CC</sub> = 0 V, Pin 8 = V<sub>EE</sub> = -5.2 V.
  - Pin 1 = Pin 15 = Pin 16 = V<sub>CC</sub> = +2.0 V, Pin 8 = V<sub>EE</sub> = -3.2 V.

10113B, F: -30 to +85°C, CERDIP

## DIGITAL 10,000 SERIES ECL

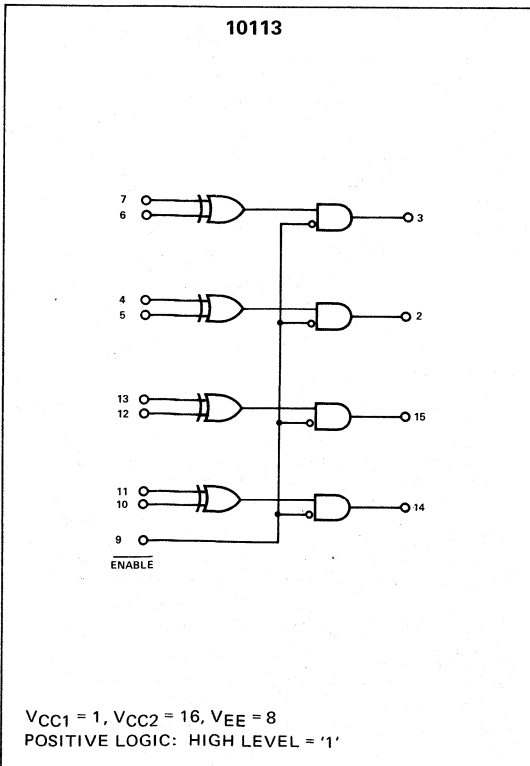
### DESCRIPTION

The 10113 is a four gate array designed to provide the positive logic Exclusive OR function in high performance applications. This device contains a temperature compensated internal bias which insures that the threshold point remains in the center of the transition region over temperature. Input pull-down resistors eliminate the need to tie unused inputs to  $V_{EE}$ .

Open emitter outputs are provided to enable bussing of multiple outputs together. If the four outputs of the 10113 are wire-ORed together the device performs a 4-bit compare function (outputs low for compare).

The outputs are all gated by the enable input. If this enable input is high all outputs will be forced low.

### LOGIC DIAGRAM



### FEATURES

- PERFORMS 4-BIT COMPARE FUNCTION (IF OUTPUTS ARE WIRE-ORed TOGETHER)
- HIGH FUNCTIONAL DENSITY — FOUR EXCLUSIVE OR GATES/PACKAGE
- FAST PROPAGATION DELAY FOR EXCLUSIVE OR: 2.5 ns TYP
- LOW POWER DISSIPATION: 165 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY — CAN DRIVE FOUR 50  $\Omega$  LINES
- HIGH Z INPUTS — INTERNAL 50 k $\Omega$  PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY
- OUTPUT ENABLE GATING MAKES POWERFUL LOGIC FUNCTION

### APPLICATIONS

- QUAD EXCLUSIVE-OR  
(For parity, error correcting, and other logic functions).
- FOUR-BIT COMPARATOR  
(For logic, test equipment, error detection applications).
- GATED FOUR-BIT COMPARATOR  
(Enable input permits wire-ORing multiples of four bits)

### TRUTH TABLE

$\overline{E9}$	IN 7	IN 6	OUT 3
L	L	L	L
L	L	H	H
L	H	L	H
L	H	H	L
H	$\phi$	$\phi$	L

$\phi$  = Don't Care.

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPES

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

**ELECTRICAL CHARACTERISTICS**

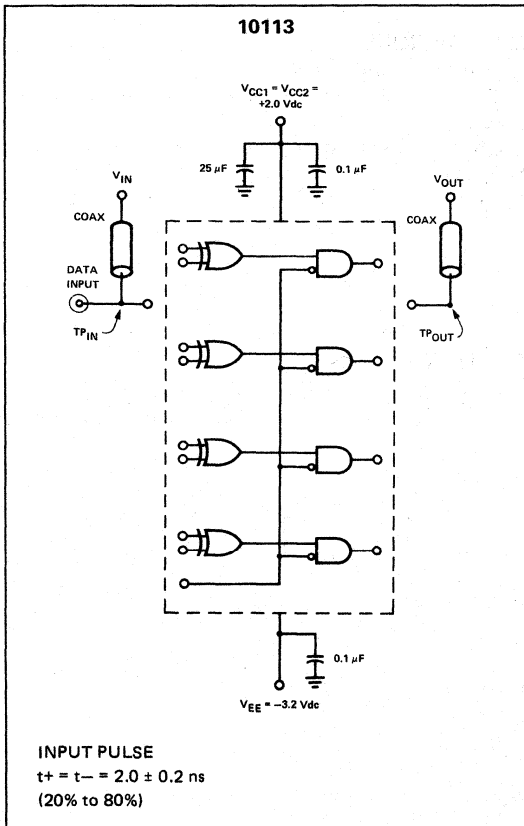
(at Listed Voltages and Ambient Temperatures).

		TEST VOLTAGE VALUES (Volts)				
@ Test Temperature		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>
-30° C		-0.890	-1.890	-1.205	-1.500	-5.2
+25° C		-0.810	-1.850	-1.105	-1.475	-5.2
+85° C		-0.700	-1.825	-1.035	-1.440	-5.2

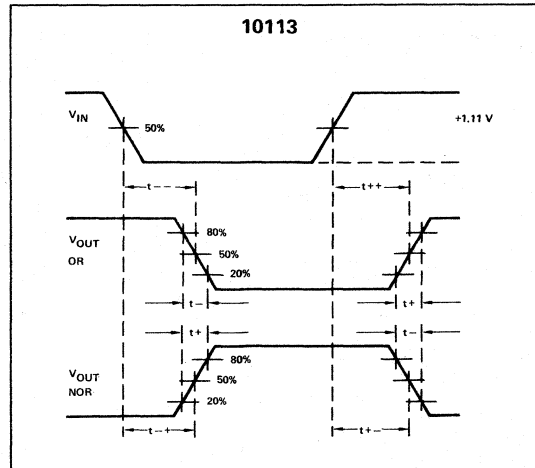
Characteristic	Symbol	Pin Under Test	10113 Test Limits						Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					Gnd									
			-30° C		+25° C		+85° C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>										
			Min	Max	Min	Max	Min	Max																
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	40	-	-	mAdc	-	-	-	-	8	1,16									
	I <sub>inH</sub>	6,7	-	-	-	265	-	-	μAdc	6,7	-	-	-	8	1,16									
		9	-	-	-	720	-	-	μAdc	9	-	-	-	8	1,16									
Logic "1" Output Voltage	V <sub>OH</sub>	3	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	Vdc	6	-	-	-	8	1,16									
		3	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	Vdc	7	-	-	-	8	1,16									
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	-	-	-	-	8	1,16									
		3	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	6,7	-	-	-	8	1,16									
Logic "1" Threshold Voltage	V <sub>OHA</sub>	3	-1.080	-	-0.980	-	-0.910	-	Vdc	-	-	6	-	8	1,16									
		3	-1.080	-	-0.980	-	-0.910	-	Vdc	-	-	7	-	8	1,16									
Logic "0" Threshold Voltage	V <sub>OLA</sub>	3	-	-1.655	-	-1.630	-	-1.595	Vdc	7	-	6	-	8	1,16									
		3	-	-1.655	-	-1.630	-	-1.595	Vdc	-	-	-	6	8	1,16									
Switching Times† (50 Ω load)	Propagation Delay	t <sub>PH</sub> t <sub>PL</sub> t <sub>HL</sub> t <sub>HL</sub>	3			Min	Typ	Max	ns	+1.11 V		Pulse In	Pulse Out	-3.2 V	+2.0 V									
						2.5										-	6	3	8	1,16				
																7	-	-	-	-	-			
																7	-	-	-	-	-			
Rise Time (20% to 80%)	t <sub>r</sub>	2,3,14,15							4,7,11,13															
																2.7			-	9	2,3,14,15	-	-	
																			2.7	-	-	-	-	-
																			2.5	-	-	-	-	-
Fall Time (20% to 80%)	t <sub>f</sub>																							
																2.5			-	-	-	-	-	

\* Individually test each input applying V<sub>IH</sub> or V<sub>IL</sub> to input under test.  
 \*\* Any Output  
 † Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25° C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a linear printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>IN</sub> to input pin and TP<sub>OUT</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10114F: -30 to 85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

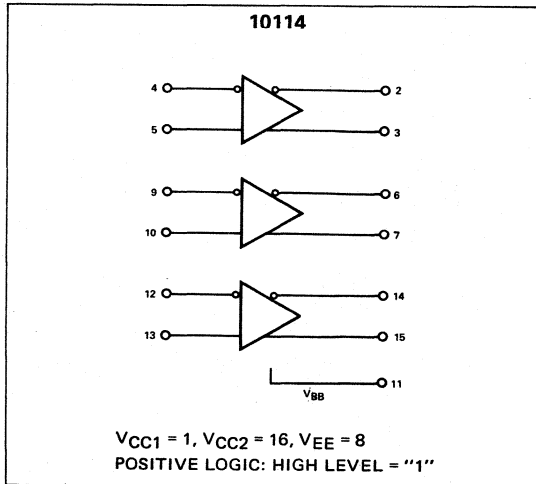
The 10114 is a triple line receiver designed for use in sensing differential signals over long lines. An active current source and translated emitter follower inputs provide the line receiver with a common mode noise rejection limit of one volt in either the positive or the negative direction. This allows a large amount of common mode noise immunity for extra long lines.

The OR outputs (pins 3, 7, 15) go to a logic low level whenever the inputs are left floating. The outputs are each capable of driving 50Ω transmission lines.

The base bias supply ( $V_{BB}$ ) is made available at pin 11 to make the device useful as a Schmitt trigger, or in other applications where a stable reference voltage is necessary.

Complementary outputs are provided to allow driving twisted pair lines, to enable cascading of several amplifiers in a chain, or simply to provide complemented outputs of the input logic function.

## LOGIC DIAGRAM



## FEATURES

- GUARANTEED COMMON MODE NOISE REJECTION
- FAST PROPAGATION DELAY = 2.0ns TYP (DIFFERENTIAL INPUT)
- OUTPUT LEVEL SPECIFIED - INPUTS OPEN
- HIGH FANOUT CAPABILITY - CAN DRIVE 50Ω LINES
- VERY HIGH INPUT Z - NO 50K PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2V \pm 5\%$  RECOMMENDED
- COMPLEMENTARY OUTPUTS
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY
- $V_{BB}$  VOLTAGE AVAILABLE ON PIN 11

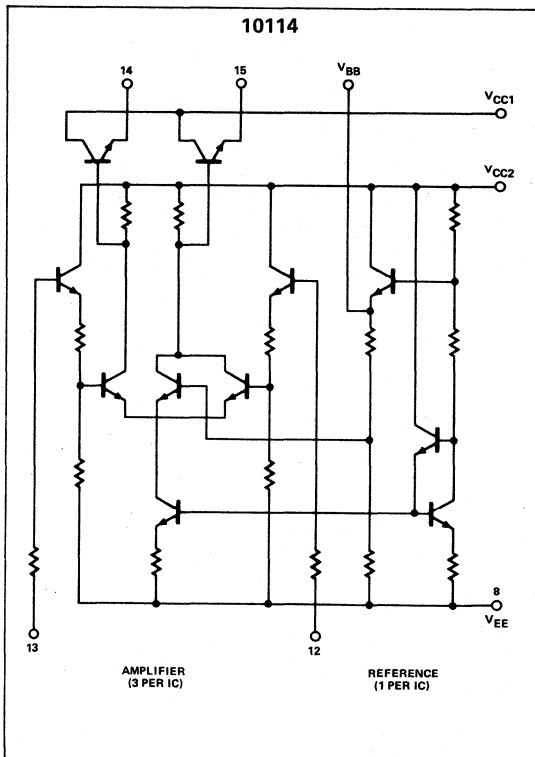
## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

## PACKAGE TYPE

F: 16-Pin CERDIP

## CIRCUIT SCHEMATIC



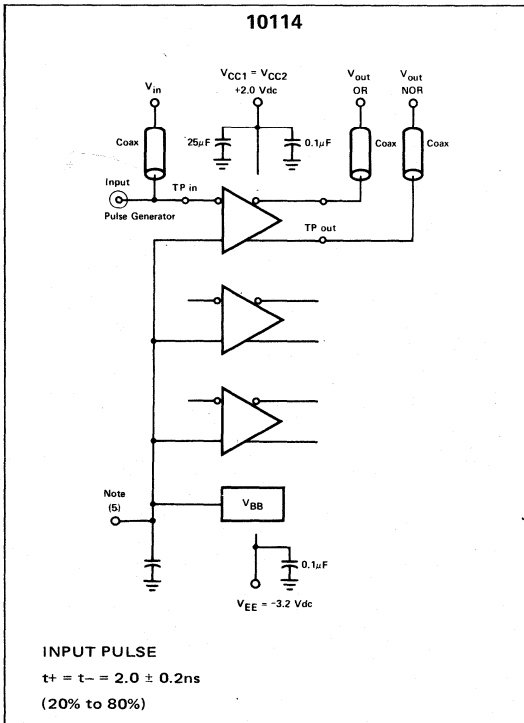
ELECTRICAL CHARACTERISTICS

At Listed Voltages and Ambient Temperatures

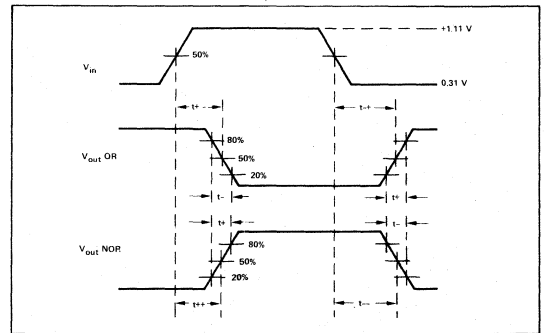
		TEST VOLTAGE VALUES																
		(Volts)																
		V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmax</sub>	V <sub>BB</sub>	V <sub>IHH</sub> *	V <sub>ILH</sub> *	V <sub>IHL</sub> *	V <sub>VLL</sub> *	V <sub>EE</sub>							
		-30°C	+25°C	+85°C														
		TEST VOLTAGE APPLIED TO PINS BELOW:																
		V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmax</sub>	V <sub>BB</sub>	V <sub>IHH</sub> *	V <sub>ILH</sub> *	V <sub>IHL</sub> *	V <sub>VLL</sub> *	V <sub>EE</sub>	Gnd						
		-0.890	-1.890	-1.205	-1.500	From	+0.110	-0.890	-1.890	-2.890	-5.2							
		-0.810	-1.850	-1.105	-1.475	Pin	+0.100	-0.850	-1.810	-2.850	-5.2							
		-0.700	-1.825	-1.035	-1.440	11	+0.300	-0.825	-1.700	-2.825	-5.2							
Characteristic	Symbol	Pin	Under Test	10114 Test Limits				Unit										
				Min	Max	Typ	Max		Min	Max	Min	Max	Min	Max	Min	Max		
Power Supply Drain Current	I <sub>E</sub>	8	-	-	28	35	-	mAde	-	4, 9, 12	-	-	-	-	8	1.16		
Input Current	I <sub>inH</sub>	4	-	-	-	45	-	μAde	4	9, 12	-	-	-	-	8	1.16		
	I <sub>CBO</sub>	4	-	-	-	1.0	-	μAde	-	9, 12	-	-	-	-	8, 4	1.16		
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	4	9, 12	-	-	8	1.16		
		3	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	9, 12	4	-	-	8	1.16		
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	9, 12	4	-	-	8	1.16		
		3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	4	9, 12	-	-	8	1.16		
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-0.910	-	-	Vdc	-	9, 12	4	-	8	1.16		
		3	-1.080	-	-0.980	-	-0.910	-	-	Vdc	9, 12	-	4	-	8	1.16		
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	-	-1.655	-	-1.630	-	-1.595	-	Vdc	9, 12	-	4	-	8	1.16		
		3	-	-1.655	-	-1.630	-	-1.595	-	Vdc	-	9, 12	4	-	8	1.16		
Reference Voltage	V <sub>BB</sub>	11	-1.420	-1.280	-1.350	-	-1.230	-1.295	-1.150	Vdc	-	-	-	-	8	1.16		
Common Mode Rejection Test *	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	-	-	4	5	-	9	1.16	
		3	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	-	-	-	5	4	8	1.16	
		2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	-	-	-	5	4	8	1.16
		3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	-	-	4	5	8	1.16	
Switching Times (50-ohm Load)																		
Propagation Delay **		14+2+	2	-	-	2.5	-	-	-	ns	-	-	Pulse in	Pulse out	-3.2 V	+2.0 V		
		14-2-	2	-	-	2.5	-	-	-	ns	-	-	4	2	5, 10, 13	-	8	1.16
		14+3-	3	-	-	2.5	-	-	-	ns	-	-	4	3	5, 10, 13	-	8	1.16
		14-3+	3	-	-	2.5	-	-	-	ns	-	-	4	3	5, 10, 13	-	8	1.16
Rise Time (20% to 80%)		t <sub>2+</sub>	2	-	-	2.1	-	-	-	ns	-	-	4	2	5, 10, 13	-	8	1.16
		t <sub>3+</sub>	3	-	-	2.1	-	-	-	ns	-	-	4	3	5, 10, 13	-	8	1.16
Fall Time (20% to 80%)		t <sub>2-</sub>	2	-	-	2.1	-	-	-	ns	-	-	4	2	5, 10, 13	-	8	1.16
		t <sub>3-</sub>	3	-	-	2.1	-	-	-	ns	-	-	4	3	5, 10, 13	-	8	1.16

- \*\* V<sub>IHH</sub> = Input logic "1" level shifted positive one volt for common mode rejection tests.
- V<sub>ILH</sub> = Input logic "0" level shifted positive one volt for common mode rejection tests.
- V<sub>IHL</sub> = Input logic "1" level shifted negative one volt for common mode rejection tests.
- V<sub>VLL</sub> = Input logic "0" level shifted negative one volt for common mode rejection tests.
- \*\* Delay is 2.0ns with differential input.
- \* Unused outputs connected to a 50-ohm resistor to ground.

SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 3mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- One input from each gate must be tied to V<sub>BB</sub> (Pin 11) during testing.



#### DESCRIPTION

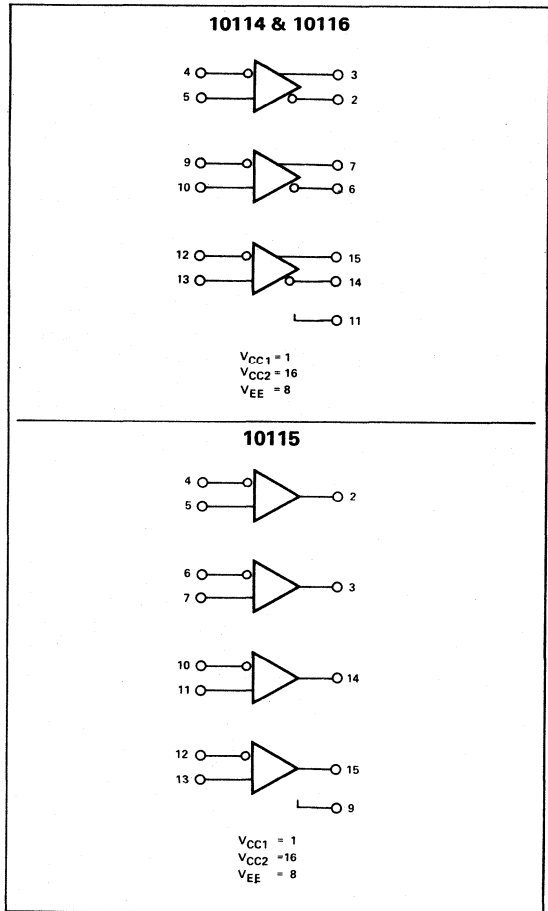
The 10114/115/116 are differential amplifiers having unloaded emitter follower outputs. The output emitter followers are capable of driving 24mA with a typical voltage swing of 800 mV. Single-ended input voltage gain is 5.4V/V, with the unity gain point occurring above 150 MHz. The 10114 and 10116 are triple differential amplifiers with complimentary outputs. The 10115 is a quad differential amplifier with single-ended outputs. An input reference bias supply ( $V_{BB}$ ) is available for use in the single ended input mode.

The 10114 is identical to 10116 except that its input common mode range is +0.0V to -2.2V. The 10115 and 10116 have a common mode range of -0.8 to -2.4 volts.

The 10114/115/116 have been designed to meet the ECL 10K line of Digital circuit specifications. When used as a linear circuit, the user should be aware of the following characteristics.

- The output voltage swing and output offset voltage is dependent on  $V_{EE}$ . The output offset voltage is centered between  $V_{OH}$  typically -0.89 and  $V_{OL}$  typically -1.75V.  $V_{OH}$  is dependent on temperature and loading current.  $V_{OL}$  is dependent on temperature, loading and power supply voltage. The temperature dependency of  $V_{OH}$  and  $V_{OL}$  is approximately +1.6mV/°C, and the power supply variation affects  $V_{OL}$  at a rate of approximately 100mV/V.
- The total input bias current of each differential amplifier is between 50 and 100  $\mu$ amp.
- Positive input voltages greater than +0.80V will tend to destroy the units if sufficient power is applied.
- The maximum input differential voltage should not exceed 5.8V, or destruction will occur if sufficient power is applied.
- The 10115 and 10116 unused inputs to the package should not be left open and the input common mode voltage should not be more negative than -2.4V or the current sources will saturate affecting the operation of the other amplifiers being used.
- For the 10115 and 10116 a common mode voltage greater than -0.8V will cause the internal differential pair to saturate and will result in speed as well as output voltage swing degradation.
- The 10114, 10115 and 10116 do not have input pull down resistors as the rest of the 10K circuits have.

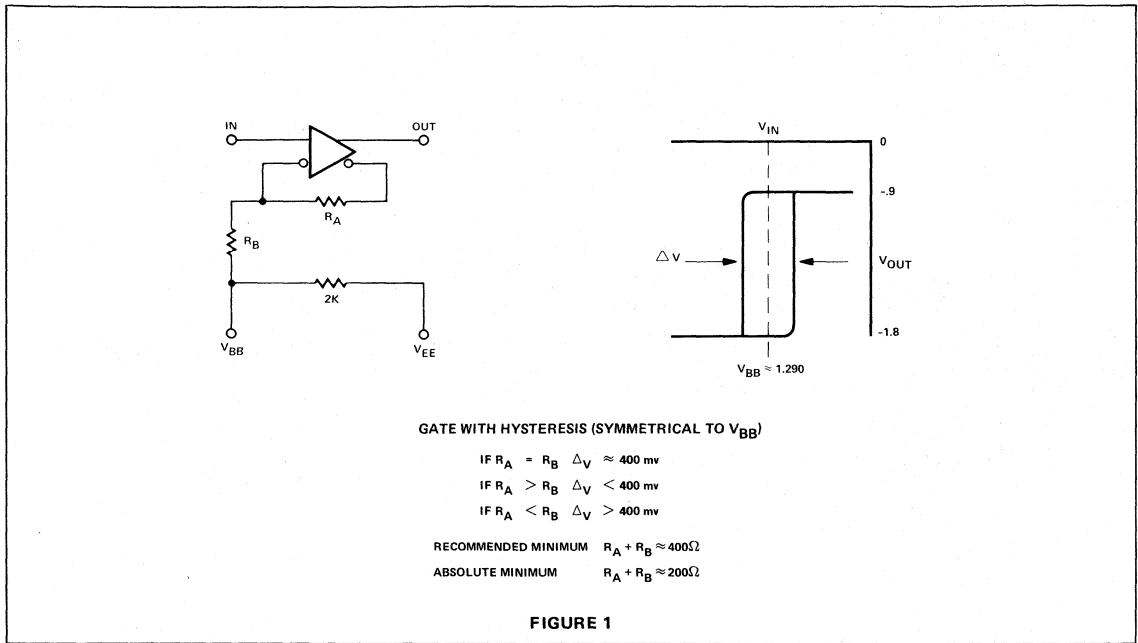
#### LOGIC SYMBOLS



#### ELECTRICAL CHARACTERISTICS

$T_A = 25^\circ\text{C}$ ,  $V_{EE} = -5.2\text{V} \pm 1\%$

	10114	10115	10116
1. $I_{EE}$	= 28 = 35	20 26	15m Adc typ. 20m Adc max.
2. $I_{inH}$	= 45	100	100 $\mu$ Adc max.
3. $t_{pd}$	= 2.5	2.0	2.0nS typ.
4. $V_{BB}$	= -1.29V typ.	Conditions: $T_A = 25^\circ\text{C}$ , $V_{CC} = +2.0\text{V} \pm 1\%$ $V_{EE} = -3.2\text{V} \pm 1\%$ , 50 ohm loads	
5. $t_r, t_f$	= 2.0nS typ. (20% to 80%)		

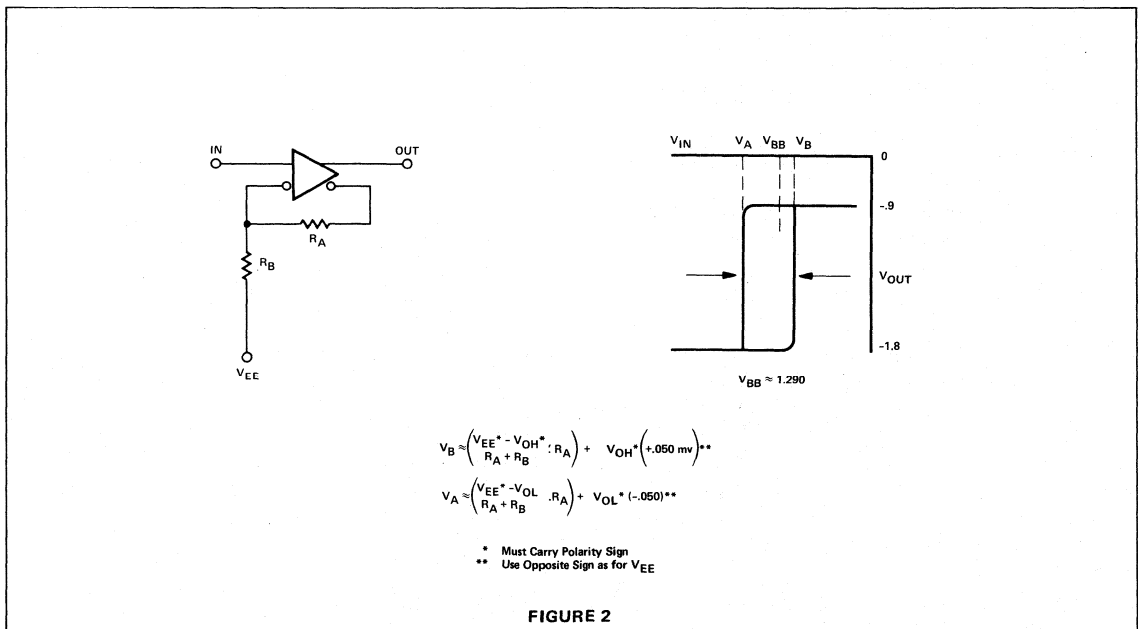


**SCHMITT-TRIGGER**

Hysteresis is a very desirable feature used to suppress noise or to restore rise and fall times after severe signal degradation has occurred due to a long transmission line or a non-square wave input. If a hysteresis gate is used to process signals using reference  $V_{BB}$ , the ckt of figure 1 is recom-

mended. Figure 2 shows a more general configuration where the center of the loop can be chosen by ckt parameters.

Note that the positive feedback required for triggering the hysteresis loop is delayed by internal propagation delays, thus on very fast input rise and fall times less than 2 nsec the regeneration will not occur and the effective input threshold will be that of the previous state.



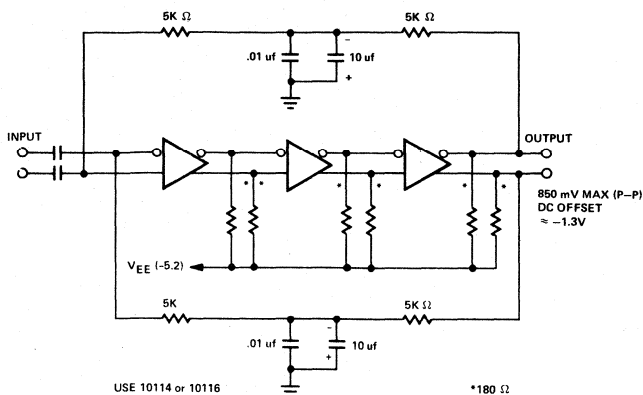


FIGURE 3

VIDEO AMPLIFIERS

The 10114/115/116 are excellent as video amplifiers. However, it is noted that the gain is affected by the power supply voltage. A higher power supply voltage will give a higher gain. The 3db point of a single stage is around

65MHz. The average gain per stage for single-ended input is approximately 5.4V/V and 10.8V/V for differential inputs. Figure 3 shows a three stage amplifier with differential inputs. Figure 4 shows a single ended version of Figure 3. Fewer stages may be employed with reduced gain.

SINGLE ENDED VIDEO DIFFERENTIAL AMP

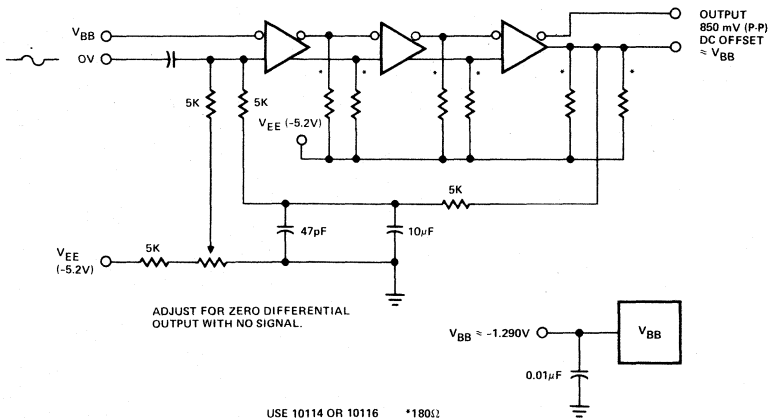
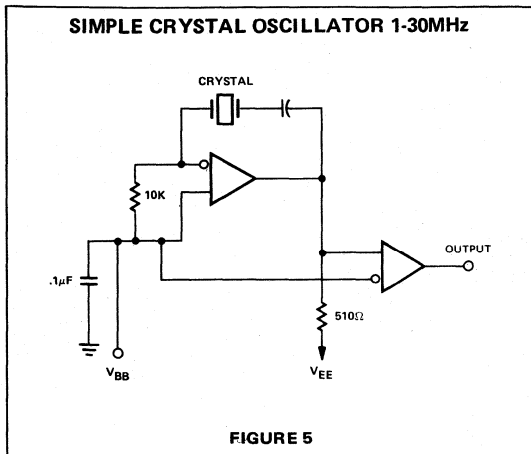


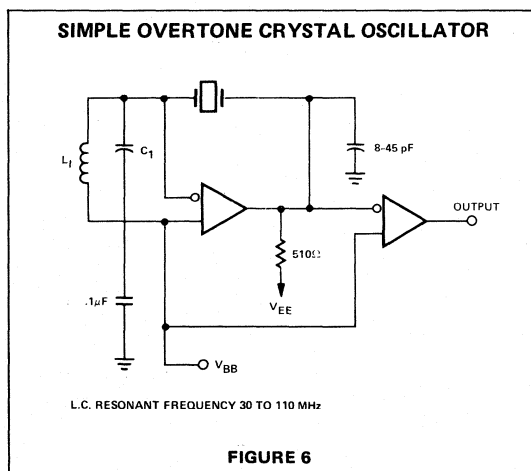
FIGURE 4



**CRYSTAL OSCILLATOR**

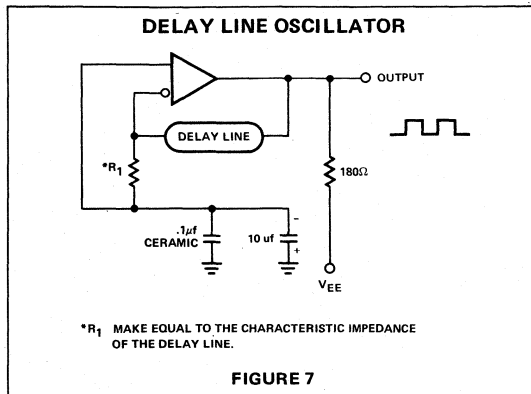
A crystal oscillator operating at the fundamental frequency of the crystal is shown in Figure 5. The crystal for this operation has to be a series resonant one. The TRIM capacitor is for fine frequency adjustments and can be replaced by a short circuit. The output of the first amplifier is nearly a sine wave and the oscillator output will be clipped sine wave. At lower frequencies, the output stage could be replaced by a symmetrical hysteresis gate as shown in Figure 1, to improve output rise and fall times.

Figure 6 shows the addition of an LC tuned circuit, used for overtone operation at frequencies higher than the fundamental.



**DELAY LINE OSCILLATOR**

Figure 7 shows a delay line oscillator. The delay line should be terminated in its characteristic impedance. Because the 10114/115/116 are designed to drive 50Ω transmission lines, the delay line can be made with a long piece of 50Ω coax cable.



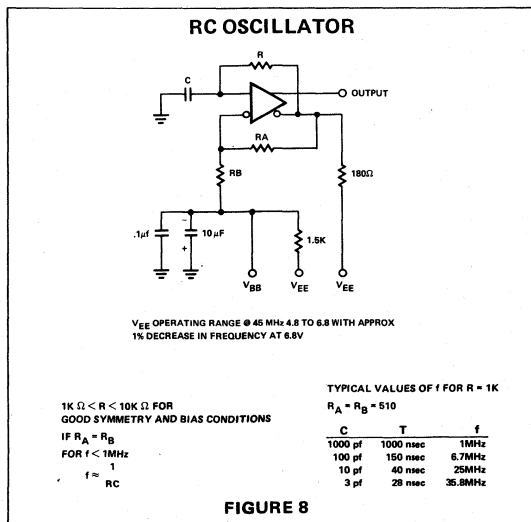
**RC OSCILLATOR**

Figure 8 shows a stable RC oscillator. R<sub>A</sub> and R<sub>B</sub> make the non-inverting side of the amplifier perform as a hysteresis gate. With R<sub>A</sub> = R<sub>B</sub> the input thresholds are set at 50% of the output voltage swing.

The period of oscillation is determined by the time it takes the inverting input to go from threshold to threshold.

Since V<sub>BB</sub> tracks with power supply variations, remaining very close to the center of the output swing, output symmetry is preserved over wide power supply variations. Frequency stability with respect to V<sub>EE</sub> changes is excellent. As the output amplitude increases with increasing V<sub>EE</sub>, the hysteresis limits widen and the rate of charge of C increases. Only a slight decrease in frequency occurs when V<sub>EE</sub> changes over the range of 4.8V to 6.8V.

The 1.5KΩ resistor from V<sub>BB</sub> to V<sub>EE</sub> trims the output symmetry and can be adjusted. It cannot be made too large due to bias considerations and if made too small, the 180Ω output load will become a substantial part of the RC time constant in the charging direction.



10115B.F: -30 to +85°C

## DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10115 is a quad differential amplifier designed for use in sensing differential signals over long lines. The base bias supply ( $V_{BB}$ ) is made available at pin 9 to make the device useful as a Schmitt trigger, or in other applications where a stable reference voltage is necessary.

Active current sources provide the 10115 with excellent common mode noise rejection. If any amplifier in a package is not used, one input must be connected to  $V_{BB}$  (pin 9) to prevent upsetting the current source bias network.

### FEATURES

- GOOD COMMON MODE NOISE REJECTION
- FAST PROPAGATION DELAY = 2.0 ns TYP
- LOW POWER DISSIPATION = 100 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
- CAN DRIVE 50  $\Omega$  LINES
- HIGH SYSTEM DENSITY - FOUR RECEIVERS PER PACKAGE
- VERY HIGH INPUT Z - NO 50 K PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 \text{ V} \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY
- $V_{BB}$  VOLTAGE AVAILABLE ON PIN 9

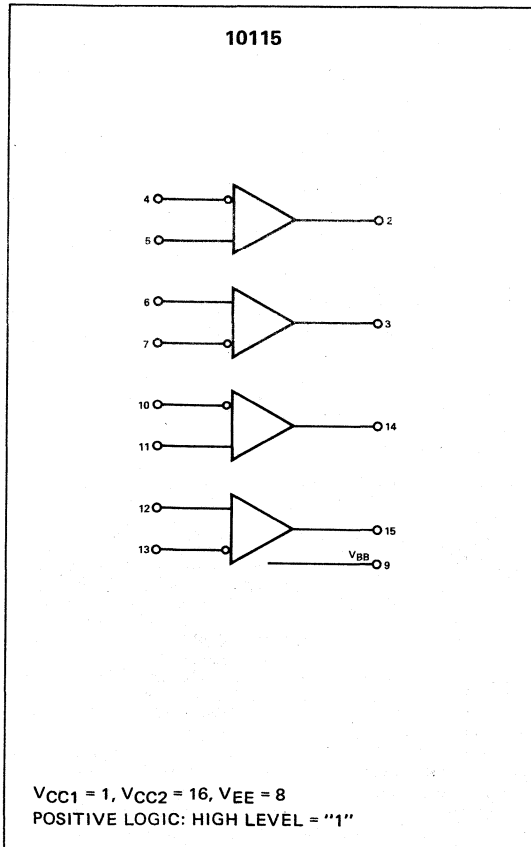
### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

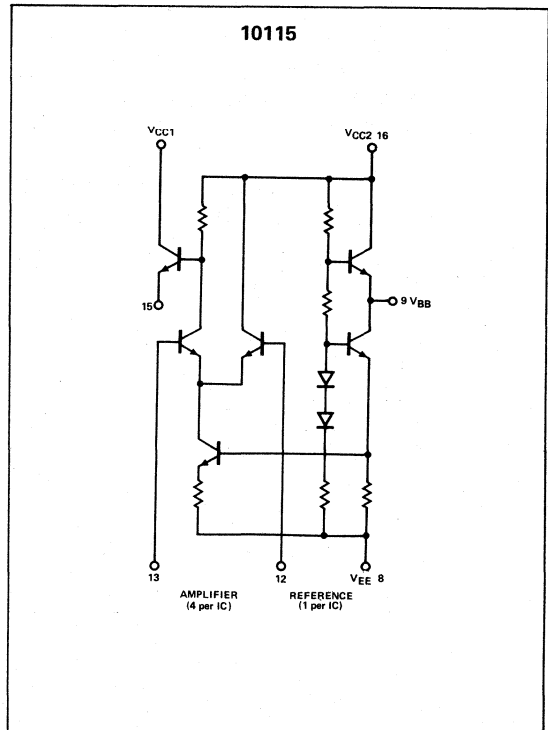
### PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

### LOGIC DIAGRAM



### CIRCUIT SCHEMATIC



**ELECTRICAL CHARACTERISTICS**

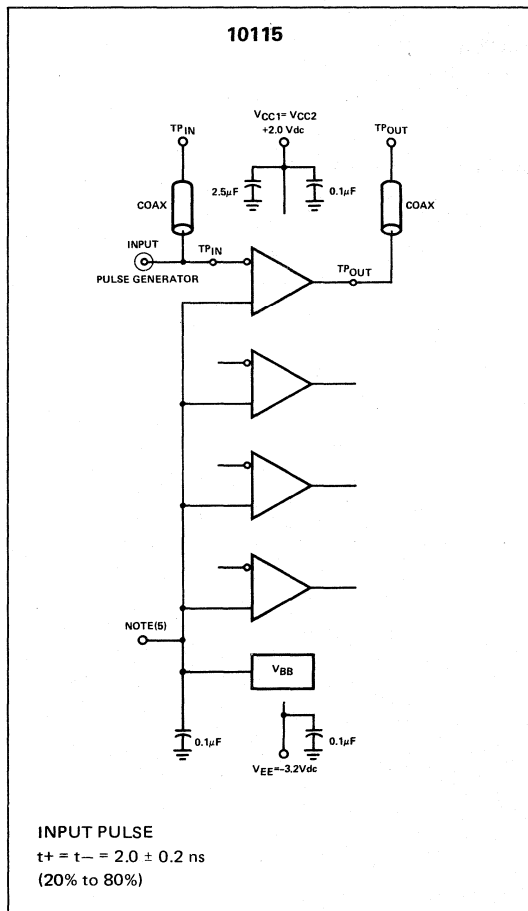
(at Listed Voltages and Ambient Temperatures).

Temperature	TEST VOLTAGE VALUES					
	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>BB</sub>	V <sub>EE</sub>
-30°C	-0.890	-1.890	-1.205	-1.500	From	-5.2
+25°C	-0.810	-1.850	-1.105	-1.475	Pin	-5.2
+85°C	-0.700	-1.825	-1.035	-1.440	9	-5.2

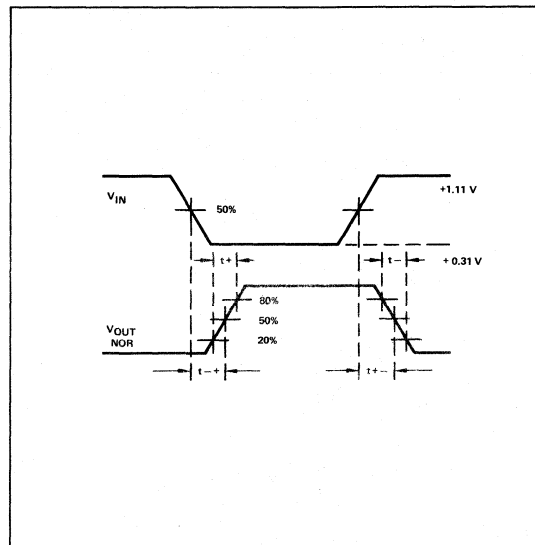
Characteristic	Symbol	Pin Under Test	10115 Test Limits						Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:						(V <sub>CC</sub> )
			-30°C		+25°C		+85°C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>BB</sub>	V <sub>EE</sub>	
			Min	Max	Min	Max	Min	Max								
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	26	-	-	mAdc	-	4,7,10,13	-	-	5,6,11,12	8	1,16
Input Current	I <sub>IH</sub>	4	-	-	-	95	-	-	μAdc	4	7,10,13	-	-	5,6,11,12	8	1,16
	I <sub>CO</sub>	4	-	-	-	1.0	-	-	μAdc	-	7,10,13	-	-	5,6,11,12	8,4	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	Vdc	7,10,13	4	-	-	5,6,11,12	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	4	7,10,13	-	-	5,6,11,12	8	1,16
Logic "1" Threshold Voltage	V <sub>QHA</sub>	2	-1.080	-	-0.980	-	-0.910	-	Vdc	-	7,10,13	-	4	5,6,11,12	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	-	-1.655	-	-1.630	-	-1.595	Vdc	-	7,10,13	4	-	5,6,11,12	8	1,16
Reference Voltage	V <sub>BB</sub>	9	1.420	1.280	-1.350	-1.230	1.295	-1.150	Vdc	-	-	-	-	5,6,11,12	8	1,16
Switching Times * (50-ohm load)																
Propagation Delay	t <sub>4-2+</sub>	2	1.0	3.1	1.0	2.9	1.0	3.3	ns	4	2			5,6,11,12	8	1,16
Rise Time (20% to 80%)	t <sub>2+</sub>	2	1.1	3.6	1.1	3.3	1.1	3.7								
Fall Time (20% to 80%)	t <sub>2-</sub>	2	1.1	3.3	1.1	3.3	1.1	3.7								

\* Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



- NOTES:**
- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
  - For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>IN</sub> to input pin and TP<sub>OUT</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
  - Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
  - All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
  - One input from each gate must be tied to V<sub>BB</sub> (Pin 9) during testing.

10116B,F: -30 to +85°C

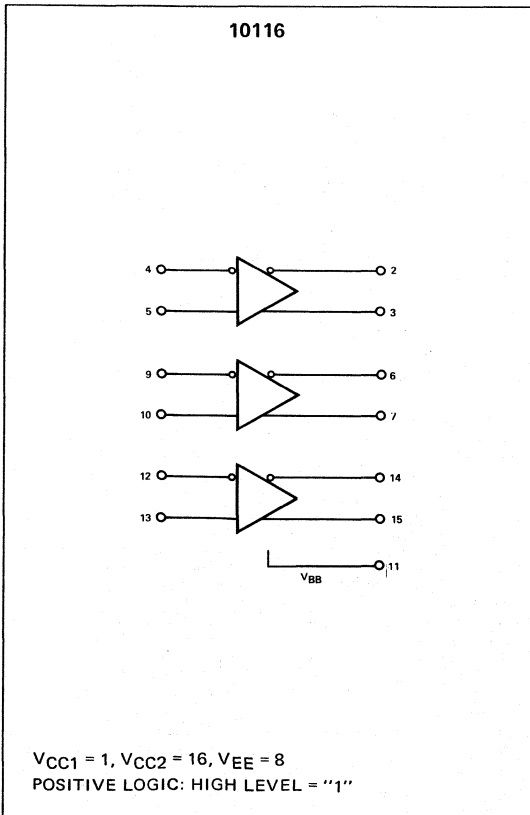
DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10116 is a triple differential amplifier designed for use in sensing differential signals over long lines. The base bias supply ( $V_{BB}$ ) is made available at pin 11 to make the device useful as a Schmitt trigger, or in other applications where a stable reference voltage is necessary. Active current sources provide the 10116 with excellent common mode noise rejection. If any amplifier in a package is not used, one input of that amplifier must be connected to  $V_{BB}$  (pin 11) to prevent upsetting the current source bias network.

Complementary outputs are provided to allow driving twisted pair lines, to enable cascading of several amplifiers in a chain, or simply to provide complemented outputs of the input logic function.

## LOGIC DIAGRAM



## FEATURES

- GOOD COMMON MODE NOISE REJECTION
- FAST PROPAGATION DELAY = 2.0 ns TYP
- LOW POWER DISSIPATION = 83 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
— CAN DRIVE 50  $\Omega$  LINES
- VERY HIGH INPUT Z — NO 50 K PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- COMPLEMENTARY OUTPUTS
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY
- $V_{BB}$  VOLTAGE AVAILABLE ON PIN 11

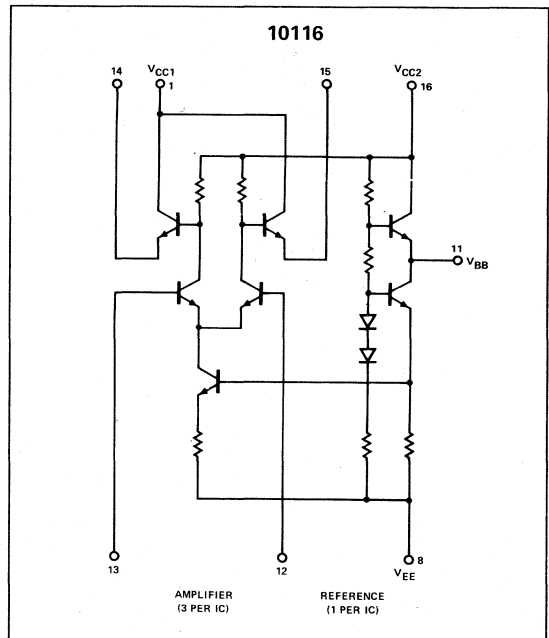
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

## CIRCUIT SCHEMATIC



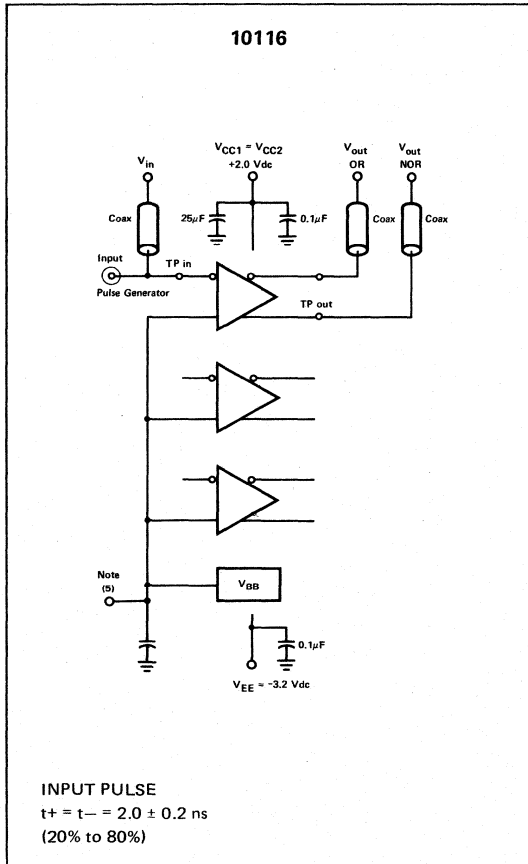
**ELECTRICAL CHARACTERISTICS**  
(At Listed Voltages and Ambient Temperatures).

TEST VOLTAGE VALUES						
(Volts)						
Symbol	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>BB</sub>	V <sub>EE</sub>
Temperature	-30°C	-1.890	-1.890	-1.205	-1.500	From Pin
	+25°C	-0.810	-1.850	-1.105	-1.475	Pin
	+85°C	-0.700	-1.825	-1.035	-1.440	11

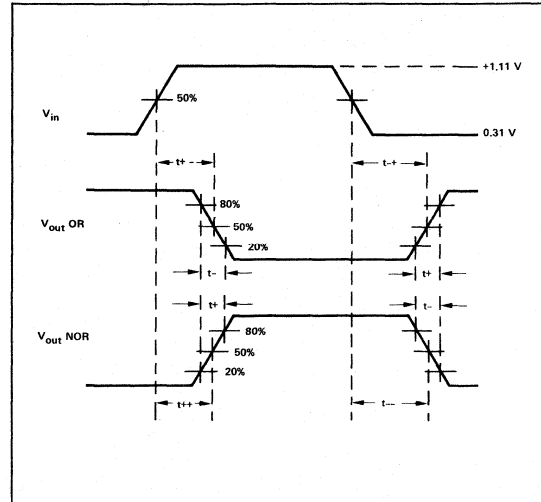
Characteristic	Symbol	Pin Under Test	10116 Test Limits						Unit	TEST VOLTAGE APPLIED TO PINS BELOW:						(V <sub>CC</sub> ) Gnd	
			-30°C		+25°C		+85°C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>BB</sub>	V <sub>EE</sub>		
			Min	Max	Min	Typ	Max	Min		Max							
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	16	20	-	-	mAdc	-	4, 9, 12	-	-	5, 10, 13	8	1, 16
	I <sub>INH</sub>	4	-	-	-	-	95	-	-	μAdc	4	9, 12	-	-	5, 10, 13	8	1, 16
	I <sub>CBO</sub>	4	-	-	-	-	1.0	-	-	μAdc	-	9, 12	-	-	5, 10, 13	8, 4	1, 16
High Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	4	9, 12	-	-	5, 10, 13	8	1, 16
		3	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	9, 12	4	-	-	5, 10, 13	8	1, 16
Low Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	9, 12	4	-	-	5, 10, 13	8	1, 16
		3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	4	9, 12	-	-	5, 10, 13	8	1, 16
High Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	9, 12	-	4	5, 10, 13	8	1, 16
		3	-1.080	-	-0.980	-	-	-0.910	-	Vdc	9, 12	-	-	4	5, 10, 13	8	1, 16
Low Threshold Voltage	V <sub>OLA</sub>	2	-	-1.855	-	-	-1.630	-	-1.595	Vdc	-	9, 12	-	4	5, 10, 13	8	1, 16
		3	-	-1.855	-	-	-1.630	-	-1.595	Vdc	9, 12	-	-	4	5, 10, 13	8	1, 16
Reference Voltage	V <sub>BB</sub>	11	-1.420	-1.280	-1.350	-	-1.230	-1.295	-1.150	Vdc	-	-	-	-	5, 10, 13	8	1, 16
Switching Times (50-ohm load)													Pulse In	Pulse Out			
Propagation Delay	t <sub>4+ 2+</sub>	2	1.0	3.1	1.0	2.0	2.9	1.0	3.3	ns	-	-	4	2	5, 10, 13	8	1, 16
	t <sub>4- 2-</sub>	2	-	-	-	-	-	-	-	-	-	-	2	2	-	-	-
	t <sub>4+ 3-</sub>	3	-	-	-	-	-	-	-	-	-	-	3	3	-	-	-
	t <sub>4- 3+</sub>	3	-	-	-	-	-	-	-	-	-	-	3	3	-	-	-
Rise Time (20% to 80%)	t <sub>2+</sub>	2	1.1	3.6	1.1	2.0	3.3	1.1	3.7	-	-	-	-	2	-	-	-
	t <sub>3+</sub>	3	-	-	-	-	-	-	-	-	-	-	-	3	-	-	-
Fall Time (20% to 80%)	t <sub>2-</sub>	2	-	-	-	-	-	-	-	-	-	-	-	2	-	-	-
	t <sub>3-</sub>	3	-	-	-	-	-	-	-	-	-	-	-	3	-	-	-

\* Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
5. One input from each gate must be tied to V<sub>BB</sub> (Pin 11) during testing.



10117B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

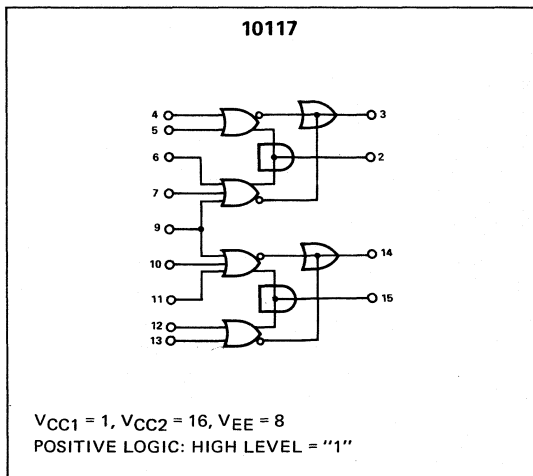
## DESCRIPTION

The 10117 package contains two 2 input/3 input OR-AND/OR-AND INVERT complex gates. Pin 9 is common to both gates. This function is particularly useful in data control, multiplexing and distribution. The 10117 is optimized for high performance applications and has an excellent speed power product. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout is ideal for a transmission line environment.

## FEATURES

- FAST PROPAGATION DELAY FOR TWO LOGIC LEVELS = 2.3 ns TYP
- POWER DISSIPATION = 100 mW/PACKAGE TYP (NO LOAD)
- VERY HIGH FANOUT CAPABILITY  
— CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS — 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY
- OUTPUTS MAY BE CROSS COUPLED BACK TO INPUTS TO MAKE A LATCH FUNCTION

## LOGIC DIAGRAM



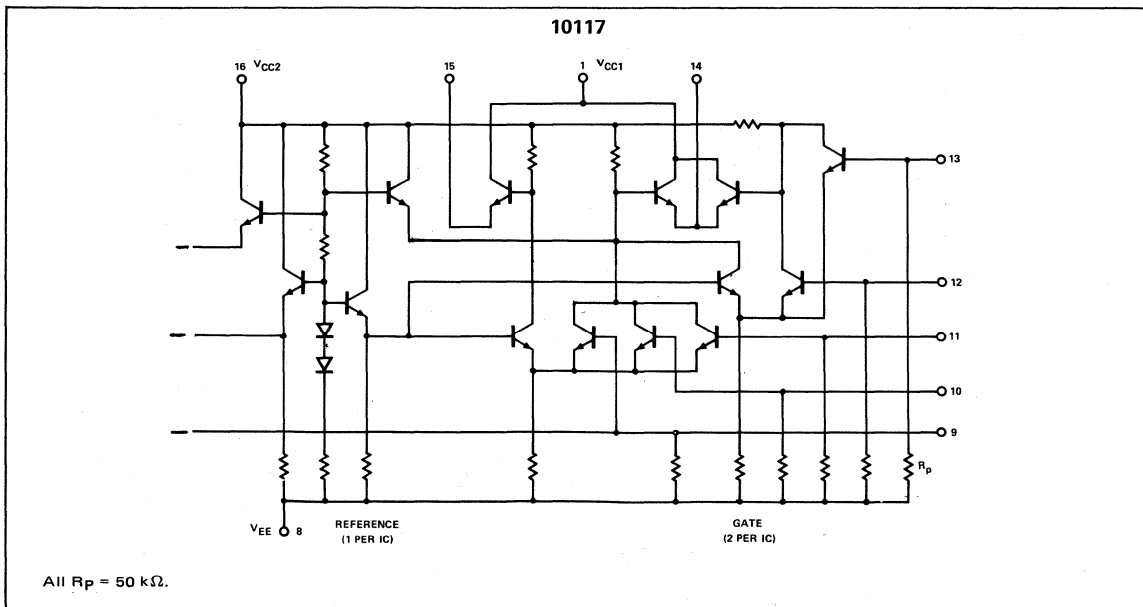
## TEMPERATURE RANGE

- -30 to +85

## PACKAGE TYPE

- B: 16 Pin Silicone DIP
- F: 16 Pin CERDIP

## CIRCUIT SCHEMATIC



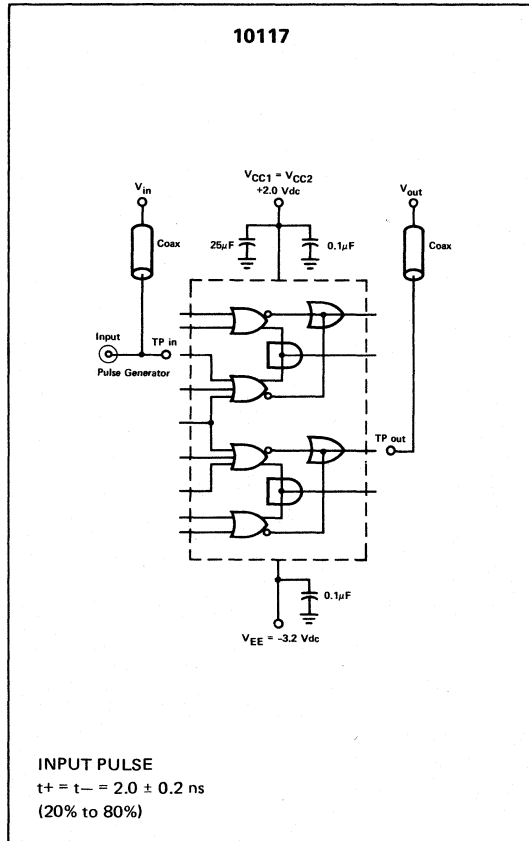
# SIGNETICS DUAL 2-WIDE 2,3-INPUT OR-AND/OR-AND-INVERT GATE ■ 10117

## ELECTRICAL CHARACTERISTICS (at Listed Voltage and Ambient Temperatures).

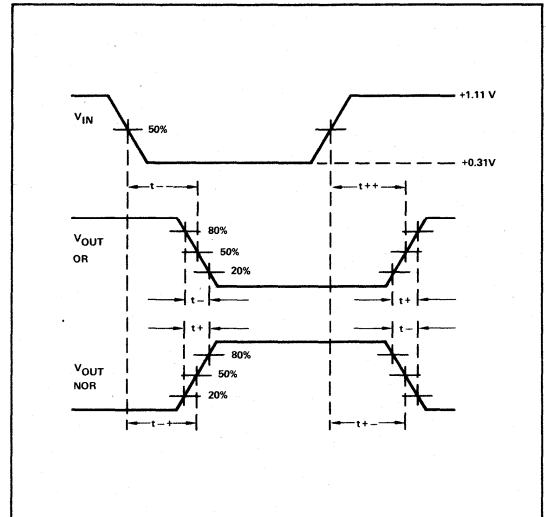
Characteristic	Symbol	Pin Under Test	10117 Test Limits												TEST VOLTAGE VALUES					(V <sub>CC</sub> ) Gnd
			-30°C			+25°C			+85°C			(Volts)								
			Min	Max	Typ	Min	Max	Min	Max	Min	Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>				
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	20	28	-	-	mAdc	4	-	-	-	8	1.16				
Input Current	I <sub>inH</sub>	4	-	-	-	285	-	-	-	μAdc	4	-	-	-	8	1.16				
	I <sub>inL</sub>	9	-	-	-	370	-	-	-	μAdc	9	-	-	-	8	1.16				
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	4,9	-	-	-	8	1.16				
	V <sub>OL</sub>	3	-1.060	-0.780	-0.960	-	-0.700	-0.890	-0.590	Vdc	4	4,9	-	-	8	1.16				
Logic "0" Output Voltage	V <sub>OH</sub>	2	-2.000	-1.675	-1.990	-	-1.650	-1.920	-1.615	Vdc	4,9	-	-	-	8	1.16				
	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	4,9	-	-	-	8	1.16				
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	9	-	4	-	8	1.16				
	V <sub>OLA</sub>	3	-1.080	-	-0.980	-	-	-0.910	-	Vdc	9	-	4	-	8	1.16				
Logic "0" Threshold Voltage	V <sub>OHA</sub>	2	-	-1.655	-	-	-1.630	-	-1.595	Vdc	9	-	4	4	8	1.16				
	V <sub>OLA</sub>	3	-	-1.655	-	-	-1.630	-	-1.595	Vdc	9	-	4	-	8	1.16				
Switching Times * (50-ohm load)											+1.11 V		Pulse In	Pulse Out	-3.2 V	+2.0 V				
Propagation Delay	t <sub>4+2+</sub>	2	1.4	3.9	1.4	2.3	3.4	1.4	3.8	ns	9	-	4	2	8	1.16				
	t <sub>4-2-</sub>	2	↓	↓	↓	↓	↓	↓	↓				2	2						
	t <sub>4+3-</sub>	3	↓	↓	↓	↓	↓	↓	↓				3	3						
	t <sub>4-3+</sub>	3	↓	↓	↓	↓	↓	↓	↓				3	3						
Rise Time (20% to 80%)	t <sub>2+</sub>	2	0.9	4.1	1.1	2.2	4.0	1.1	4.6				2	2						
	t <sub>3+</sub>	3	↓	↓	↓	↓	↓	↓	↓				3	3						
Fall Time (20% to 80%)	t <sub>2-</sub>	2	↓	↓	↓	↓	↓	↓	↓				2	2						
	t <sub>3-</sub>	3	↓	↓	↓	↓	↓	↓	↓				3	3						

\*Unused outputs connected to a 50-ohm resistor to ground.

### SWITCHING TIME TEST CIRCUIT



### PROPAGATION DELAY WAVEFORMS @ 25°C



#### NOTES:

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10118B, F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

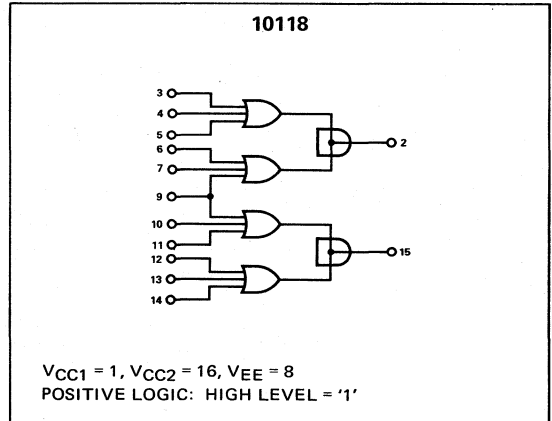
## DESCRIPTION

The 10118 package contains two 3,3-input OR-AND Complex gates. Pin 9 is common to both gates. This function is particularly useful in data control, multiplexing and data distribution. The 10118 is optimized for high performance applications and has an excellent speed power product. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout is ideal for a transmission line environment. This gate meets the ECL 10,000 Series current and rise and fall time specifications.

## FEATURES

- FAST PROPAGATION DELAY FOR 2 LOGIC LEVELS = 2.3 ns TYP
- LOW POWER DISSIPATION = 100 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
- CAN DRIVE 50 Ω LINE
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>CC</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

## LOGIC DIAGRAM



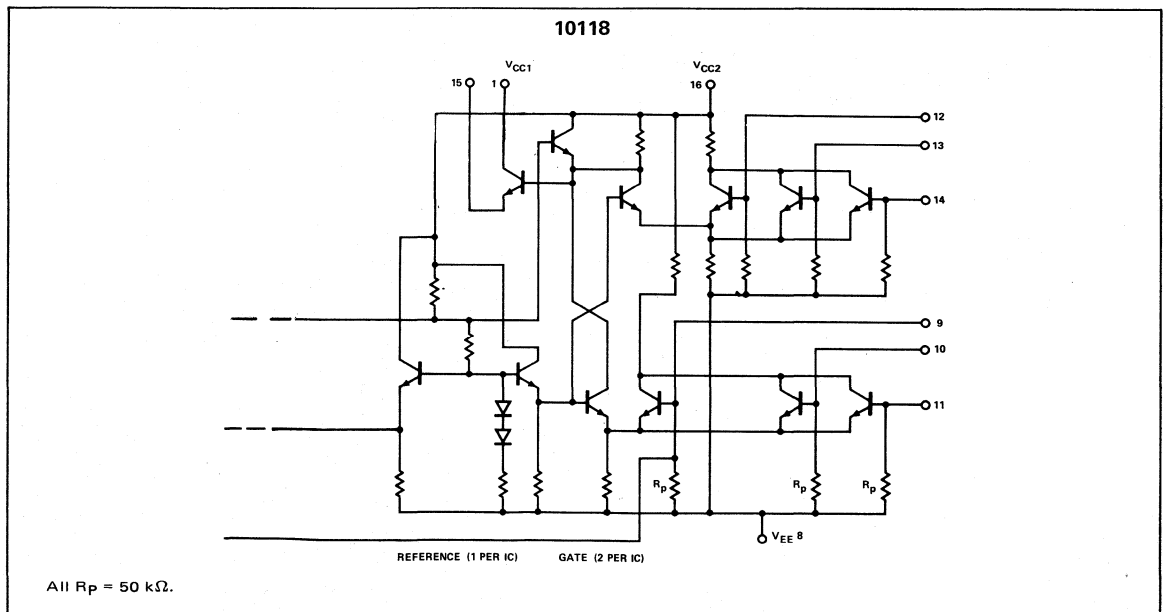
## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

## CIRCUIT SCHEMATIC



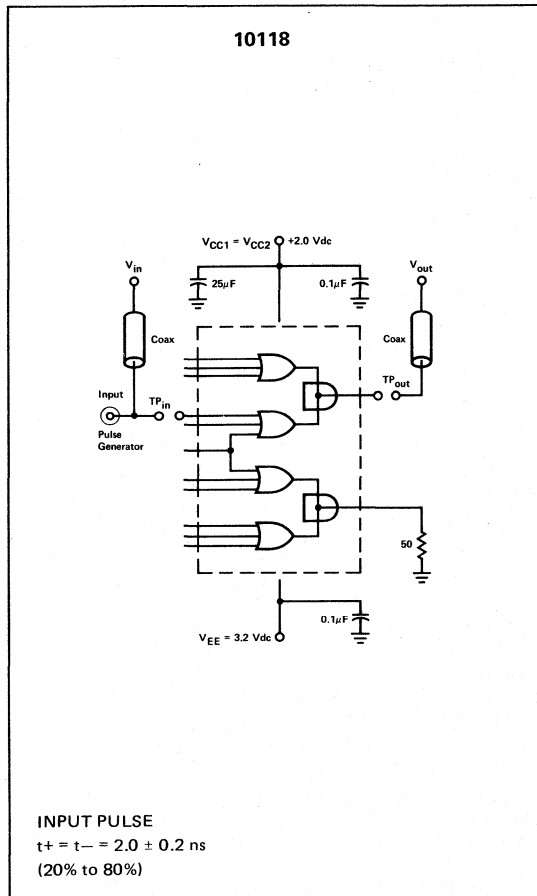
**ELECTRICAL CHARACTERISTICS**  
(at Listed Voltages and Ambient Temperatures).

TEST VOLTAGE VALUES				
(Volts)				
VIH max	VIL min	VIHA min	VILA max	VEE
-0.890	-1.890	-1.205	-1.500	-5.2
-0.810	-1.850	-1.105	-1.475	-5.2
-0.700	-1.825	-1.035	-1.440	-5.2

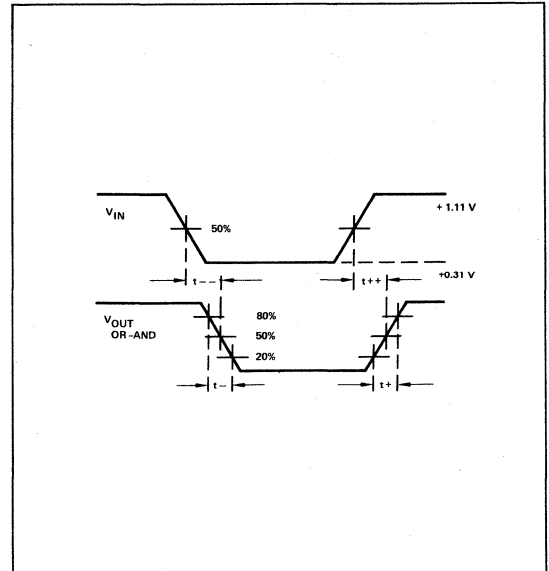
Characteristic	Symbol	Pin Under Test	10118 Test Limits								Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(VCC) Gnd
			-30°C		+25°C		+85°C		VIH max	VIL min		VIHA min	VILA max	VEE			
			Min	Max	Min	Typ	Max	Min							Max		
Power Supply Drain Current	IE	8	-	-	-	20	26	-	-	mAdc	-	-	-	-	8	1,16	
Input Current	IinH	6	-	-	-	-	265	-	-	μAdc	6	-	-	-	8	1,16	
		7	-	-	-	-	265	-	-	μAdc	7	-	-	-	8	1,16	
		9	-	-	-	-	370	-	-	μAdc	9	-	-	-	8	1,16	
Input Current	IinL	6	-	-	0.5	-	-	-	-	μAdc	-	6	-	-	8	1,16	
		7	-	-	-	-	-	-	-	μAdc	-	7	-	-	8	1,16	
		9	-	-	-	-	-	-	-	μAdc	-	9	-	-	8	1,16	
Logic "1" Output Voltage	VOH	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	3,9	-	-	-	8	1,16	
Logic "0" Output Voltage	VOL	2	-2.000	-1.675	-1.990	-	-1.650	-1.920	-1.615	Vdc	-	3,9	-	-	8	1,16	
Logic "1" Threshold Voltage	VOHA	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	9	-	3	-	8	1,16	
Logic "0" Threshold Voltage	VOLA	2	-	-1.655	-	-	-1.630	-	-1.595	Vdc	9	-	-	3	8	1,16	
Switching Times* (50-ohm load)											+1.11 V		Pulse In	Pulse Out	-3.2 V	+2.0 V	
Propagation Delay	t6+ 2+	2	1.4	3.9	1.4	2.3	3.4	1.4	3.8	ns	3	-	6	2	8	1,16	
	t6- 2-		1.4	3.9	1.4	2.3	3.4	1.4	3.8								
Rise Time (20% to 80%)	t+		0.8	4.1	1.5	2.5	4.0	1.5	4.6								
Fall Time (20% to 80%)	t-		0.8	4.1	1.5	2.5	4.0	1.5	4.6								

\* Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10119B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

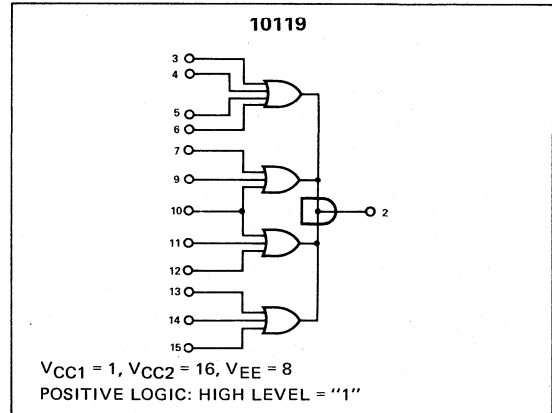
## DESCRIPTION

The 10119 is a 4 wide 4-3-3-3 input OR-AND gate. Pin 10 is common to two of the input gates. This function is particularly useful in data control and multiplexing. The 10119 is optimized for high performance applications and has an excellent speed power product. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout is ideal for a transmission line environment.

## FEATURES

- FAST PROPAGATION DELAY FOR 2 LOGIC LEVELS = 2.3 ns TYP
- LOW POWER DISSIPATION = 100 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
- CAN DRIVE 50 Ω LINE
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

## LOGIC DIAGRAM



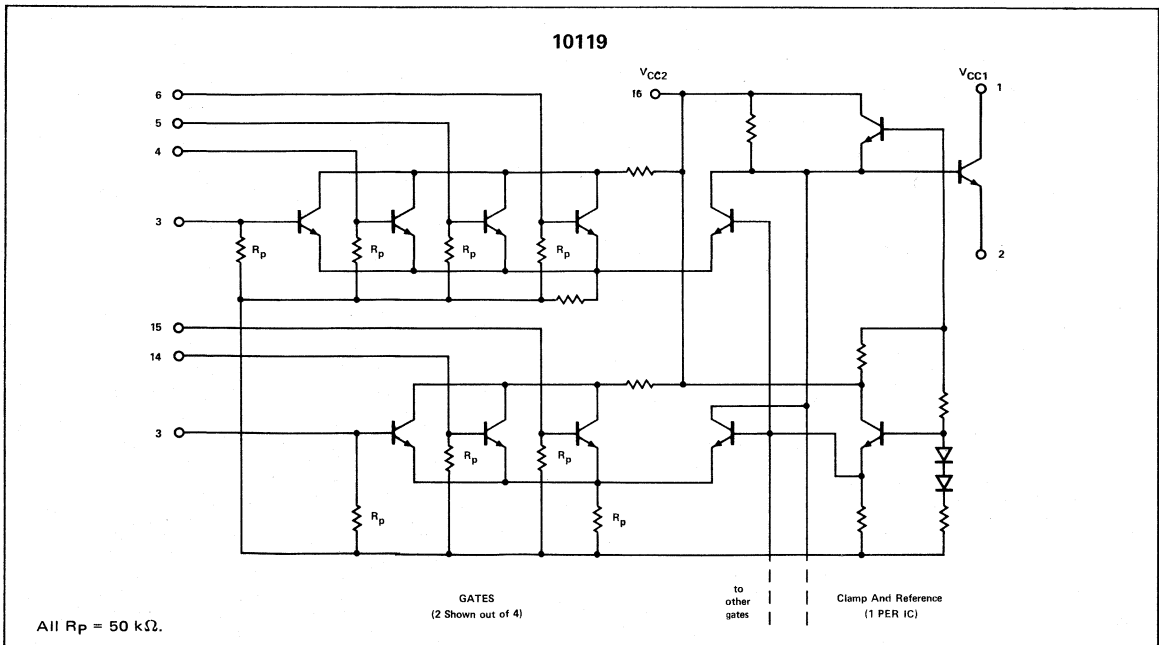
## TEMPERATURE RANGE

-30 to +85

## PACKAGE TYPE

B: 16-Pin Silicone DIP  
F: 16-Pin CERDIP

## CIRCUIT SCHEMATIC



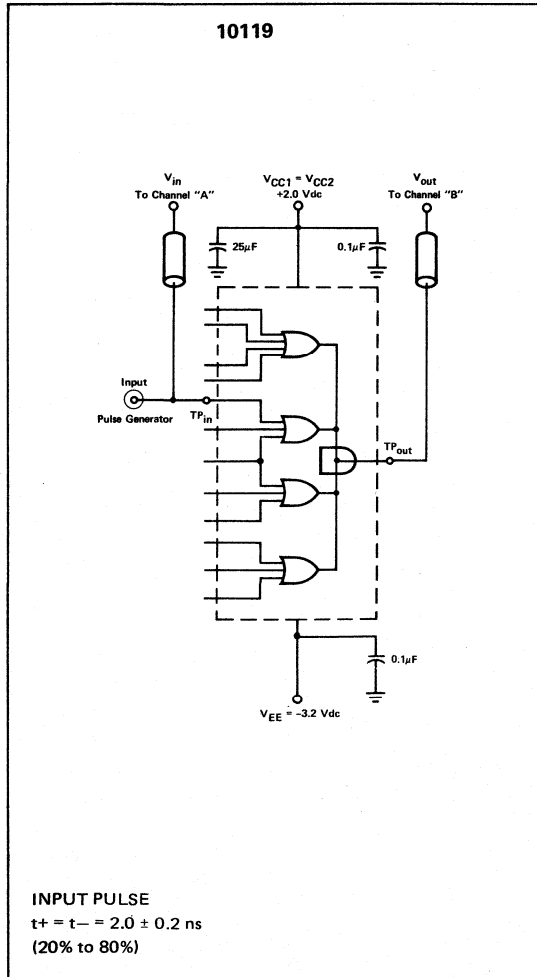
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

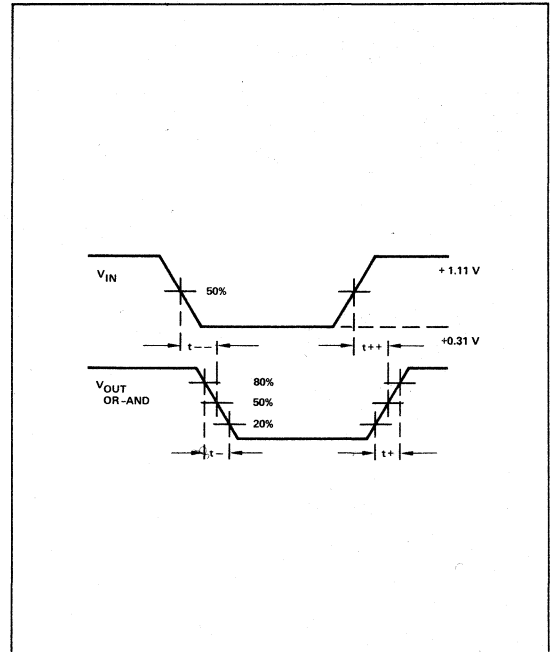
Characteristic	Symbol	Pin Under Test	10119 Test Limits									TEST VOLTAGE VALUES					(V <sub>CC</sub> ) Gnd
			-30°C			+25°C			+85°C			(Volts)					
			Min	Max	Typ	Min	Max	Min	Max	Min	Max	Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	20	26	-	-	-	mAdc	-	-	-	-	8	1,16
Input Current	I <sub>inH</sub>	7	-	-	-	-	265	-	-	-	μAdc	7	-	-	-	8	1,16
		9	-	-	-	-	265	-	-	-	μAdc	9	-	-	-	8	1,16
		10	-	-	-	-	370	-	-	-	μAdc	10	-	-	-	8	1,16
Input Current	I <sub>inL</sub>	7	-	-	0.5	-	-	-	-	-	μAdc	-	7	-	-	8	1,16
		9	-	-	-	-	-	-	-	-	μAdc	-	9	-	-	8	1,16
		10	-	-	-	-	-	-	-	-	μAdc	-	10	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	-	Vdc	3,10,15	-	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	2	-2.000	-1.675	-1.990	-	-1.650	-1.920	-1.615	-	Vdc	-	3,10,15	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	-	Vdc	10,15	-	3	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	-	-1.655	-	-	-1.630	-	-1.595	-	Vdc	10,15	-	-	3	8	1,16
Switching Times * (50-ohm load)												+1.11 V		Pulse In	Pulse Out	-3.2 V	+2.0 V
Propagation Delay	t <sub>3+2+</sub>	2	1.4	3.9	1.4	2.3	3.4	1.4	3.8	ns	10,13	-	3	2	8	1,16	
	t <sub>3-2-</sub>		1.4	3.9	1.4	2.3	3.4	1.4	3.8		10,13	-					
Rise Time (20% to 80%)	t <sub>r</sub>		0.8	4.1	1.5	2.5	4.0	1.5	4.6								
Fall Time (20% to 80%)	t <sub>f</sub>		0.8	4.1	1.5	2.5	4.0	1.5	4.6								

\*Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 2 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

## 4-WIDE 3,3,3-INPUT OR-AND/OR-AND-INVERT GATE 10121

10121B,F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10121 is a 4 wide 3-3-3-input OR-AND/OR-AND-INVERT gate. Pin 10 is common to two of the input gates. This function is particularly useful in data control and multiplexing. The 10121 is optimized for high performance applications and has an excellent speed power product. All inputs are terminated with a 50 kΩ resistor to V<sub>EE</sub> which eliminates the need to tie unused inputs low. The high impedance inputs and high output fanout is ideal for a transmission line environment.

### FEATURES

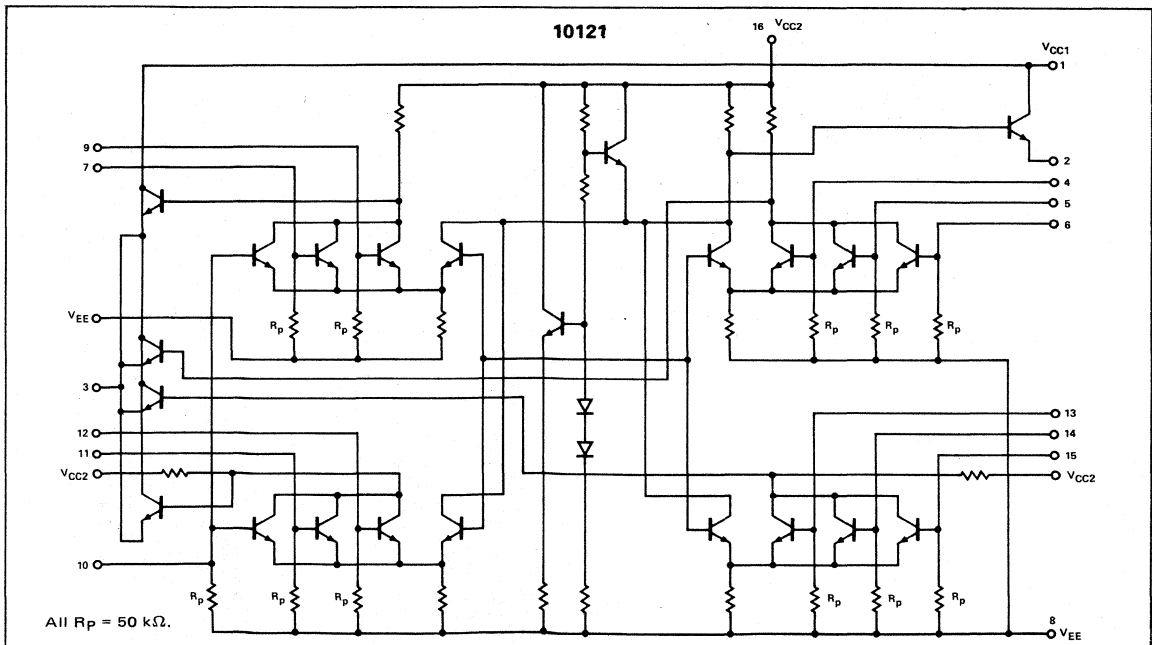
- FAST PROPAGATION DELAY FOR 2 LOGIC LEVELS = 2.3 ns TYP
- LOW POWER DISSIPATION = 100 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY
  - CAN DRIVE TWO 50 Ω LINES
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

### EQUATIONS (Positive Logic)

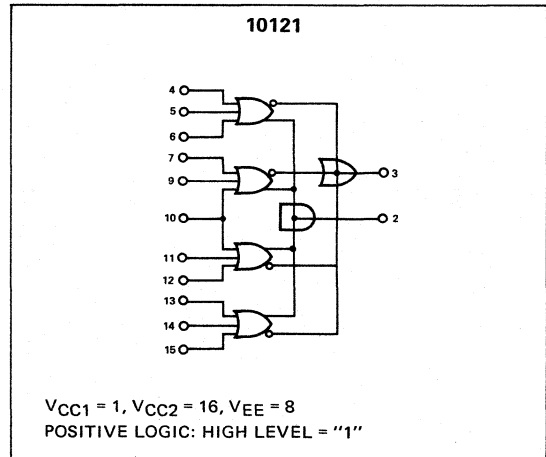
$$2 = (4+5+6) \cdot (7+9+10) \cdot (10+11+12) \cdot (13+14+15)$$

$$3 = \frac{(4+5+6) + (7+9+10) + (10+11+12) + (13+14+15)}{(4+5+6) \cdot (7+9+10) \cdot (10+11+12) \cdot (13+14+15)}$$

### CIRCUIT SCHEMATIC



### LOGIC DIAGRAM



### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- B: 16-Pin Silicone DIP
- F: 16-Pin CERDIP

# SIGNETICS 4-WIDE 3,3,3-INPUT OR-AND/OR-AND-INVERT GATE ■ 10121

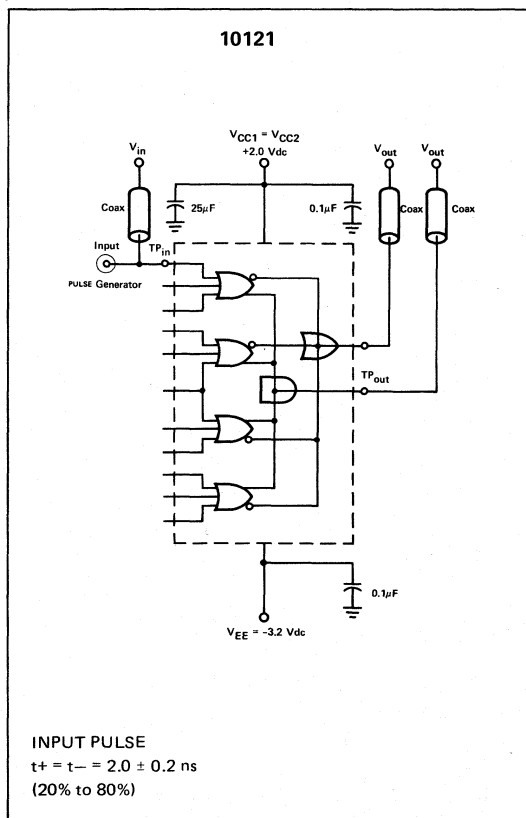
## ELECTRICAL CHARACTERISTICS

(at Listed Voltage and Ambient Temperatures).

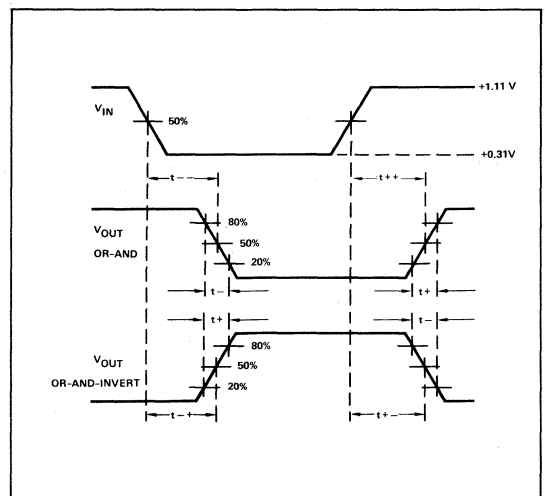
Characteristic	Symbol	Pin Under Test	10121 Test Limits						TEST VOLTAGE VALUES					Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					V <sub>CC</sub> Gnd
			-30°C		+25°C		+85°C		(Volts)						V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VILA</sub> max	V <sub>EE</sub>	
			Min	Max	Min	Typ	Max	Min	Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VILA</sub> max							
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	20	26	-	-	-	-	-	-	-	-	-	-	-	8	1,16
Input Current	I <sub>inH</sub>	7	-	-	-	265	-	-	-	-	-	7	-	-	-	-	-	-	8	1,16
		9	-	-	-	265	-	-	-	-	-	9	-	-	-	-	-	-	8	1,16
		10	-	-	-	370	-	-	-	-	-	10	-	-	-	-	-	-	8	1,16
Input Current	I <sub>inL</sub>	7	-	-	0.5	-	-	-	-	-	-	-	7	-	-	-	-	-	8	1,16
		9	-	-	-	-	-	-	-	-	-	-	9	-	-	-	-	-	8	1,16
		10	-	-	-	-	-	-	-	-	-	-	10	-	-	-	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	3	-1.060	-0.780	-0.960	-	-0.700	-0.890	-0.590	V <sub>dcc</sub>	-	-	-	-	-	-	-	-	8	1,16
		2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	V <sub>dcc</sub>	4,10,15	-	-	-	-	-	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	V <sub>dcc</sub>	4,10,15	-	-	-	-	-	-	-	8	1,16
		2	-2.000	-1.675	-1.990	-	-1.650	-1.920	-1.615	V <sub>dcc</sub>	-	4,10,15	-	-	-	-	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	3	-1.080	-	-0.980	-	-	-0.910	-	V <sub>dcc</sub>	10,15	-	-	-	4	-	-	-	8	1,16
		2	-1.080	-	-0.980	-	-	-0.910	-	V <sub>dcc</sub>	10,15	-	4	-	-	-	-	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	3	-	-1.655	-	-	-1.630	-	-1.595	V <sub>dcc</sub>	10,15	-	4	-	-	-	-	-	8	1,16
		2	-	-1.655	-	-	-1.630	-	-1.595	V <sub>dcc</sub>	10,15	-	-	4	-	-	-	-	8	1,16
Switching Times * (50-ohm load)											+1.1 V		Pulse In	Pulse Out	-3.2 V	+2.0 V				
Propagation Delay	t <sub>4+ 3-</sub> t <sub>4- 3+</sub> t <sub>4+ 2+</sub> t <sub>4- 2-</sub>	3	1.4	3.9	1.4	2.3	3.4	1.4	3.8	ns	10,13	-	4	3	8	1,16				
		2	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓			
		3	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓			
		2	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓	↓			
Rise Time (20% to 80%)	t <sub>3+</sub> t <sub>2+</sub>	2	0.9	4.1	1.1	2.5	4.0	1.1	4.6											
		3	↓	↓	↓	↓	↓	↓	↓	↓										
Fall Time (20% to 80%)	t <sub>3-</sub> t <sub>2-</sub>	3	↓	↓	↓	↓	↓	↓	↓											
		2	↓	↓	↓	↓	↓	↓	↓											

\* Unused outputs connected to a 50-ohm resistor to ground.

## SWITCHING TIME TEST CIRCUIT



## PROPAGATION DELAY WAVEFORMS @ 25°C



### NOTES:

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 2 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.



10124 B,F: -30 to 85°C

DIGITAL 10,000 SERIES ECL

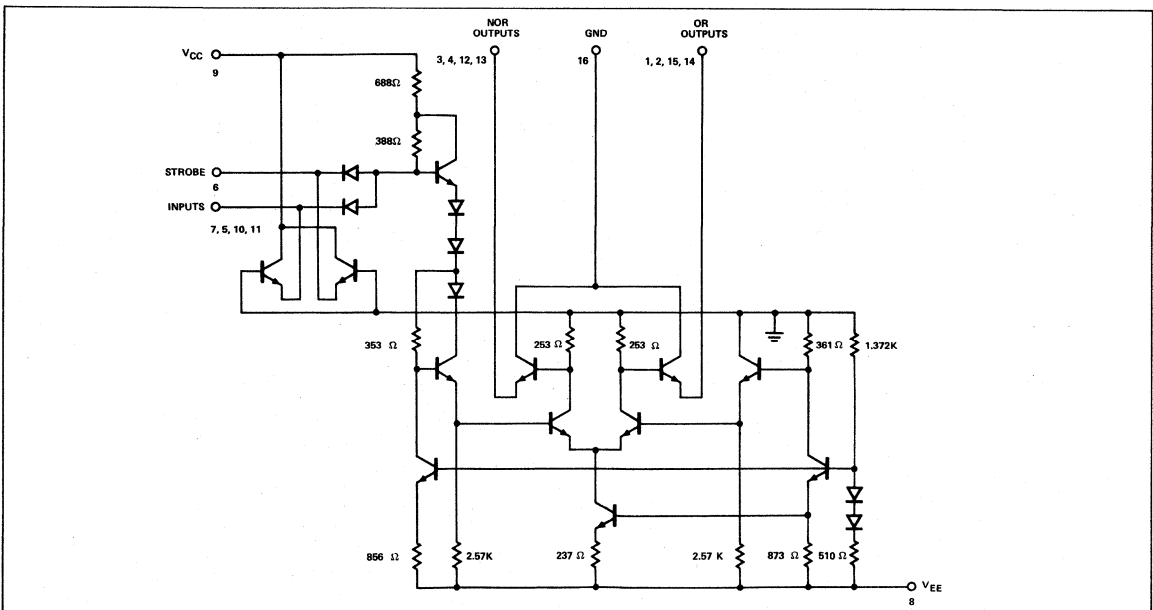
## DESCRIPTION

The 10124 is a Quad Differential Line Driver or TTL to ECL translator. The 10124 inputs are compatible with standard and Schottky TTL levels. The outputs are standard ECL 10,000 levels. Complementary open emitter outputs provide for inverting, non-inverting or differential applications. A common strobe input when at a TTL logical "0" forces all true outputs to an ECL logical "0" and all inverting outputs to an ECL logical "1".

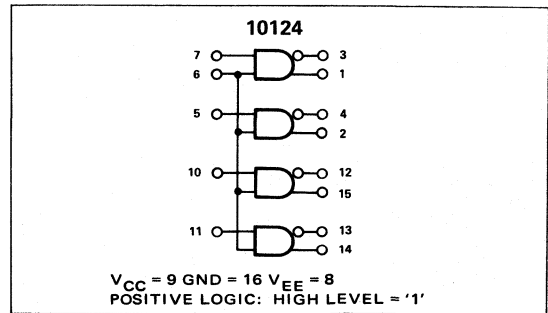
## FEATURES

- FAST PROPAGATION DELAY = 5.0 ns TYP.
- POWER DISSIPATION = 340mW/PACKAGE TYP.
- VERY HIGH FANOUT CAPABILITY
  - CAN DRIVE EIGHT 50Ω LINES
  - DC OUTPUT LOADING FACTOR OF 90X8
- COMPLEMENTARY OUTPUTS
- STANDARD ECL 10,000 SERIES OUTPUT LEVELS
- OPEN EMITTER OUTPUTS FOR BUSSING AND LOGIC CAPABILITY
- TTL COMPATIBLE INPUT STROBE
- INPUT-CLAMP DIODES
- FOUR TRANSLATORS PER PACKAGE

## CIRCUIT SCHEMATIC (1/4 OF CIRCUIT SHOWN)



## LOGIC DIAGRAM



## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

## PACKAGE TYPE

- F: 16-Pin CERDIP
- B: 16-Pin Silicone Dip

## RECOMMENDED OPERATING VOLTAGE

$V_{CC} = +5.0V \pm 5\%$ ,  $V_{EE} = 5.2V \pm 5\%$

# SIGNETICS QUAD DIFFERENTIAL LINE DRIVER ■ 10124

## ELECTRICAL CHARACTERISTICS (At Listed Voltages and Ambient Temperatures).

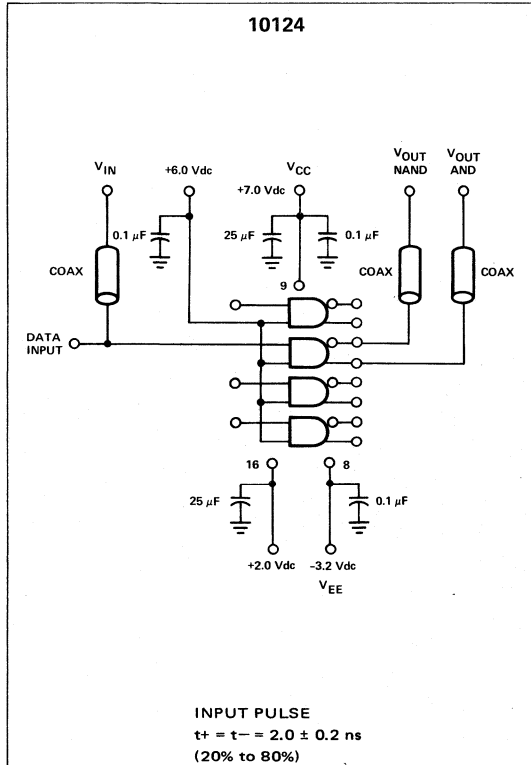
@ Test Temperature  
-30°C  
+25°C  
+85°C

Characteristic		Symbol	Pin Under Test	10124 Test Limits						TEST VOLTAGE/CURRENT VALUES									
				-30°C		+25°C		+85°C		VOLTS									
				Min.	Max.	Min.	Max.	Min.	Max.	V <sub>IH</sub>	V <sub>ILmax</sub>	V <sub>IHA'</sub>	V <sub>ILA'</sub>	V <sub>F</sub>	V <sub>R</sub>	V <sub>CC</sub>	V <sub>EE</sub>	I <sub>I</sub>	I <sub>in</sub>
Negative Power Supply Drain Current	I <sub>F</sub>	8	--	--	--	-66	--	--	mAdc	5,6,7,10,11	--	--	--	--	9	8	--	--	16
Positive Power Supply Drain Current	I <sub>CCH</sub> I <sub>CCL</sub>	9	--	--	--	+16	--	--	mAdc	5,6,7,10,11	--	--	--	--	9	8	--	--	16
Reverse Current	I <sub>R</sub>	7	--	--	--	400	--	--	μAdc	5,7,10,11	6	9	8	9	8	8	--	--	16
Forward Current	I <sub>F</sub>	6	--	--	--	-12.8	--	--	mAdc	5,7,10,11	--	--	--	6	9	8	--	--	16
Input Breakdown Voltage	BV <sub>in</sub>	6 7	--	--	+5.5	--	--	--	Vdc	6	--	--	--	9	8	6	7	5,7,10,11,16	6,16
Clamp Input Voltage	V <sub>I</sub>	6 7	--	--	-1.2	--	--	--	Vdc	6	--	--	--	9	8	6	7	--	16
High Output Voltage	V <sub>OH</sub>	1 3	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	Vdc	6,7	--	--	--	9	8	--	--	16	
Low Output Voltage	V <sub>OL</sub>	1 3	-1.890	-1.675	-1.850	-1.660	-1.825	-1.615	Vdc	6,7	6,7	--	--	9	8	--	--	16	
High Threshold Voltage	V <sub>OHA</sub>	1 3	-1.080	--	-0.980	--	-0.910	--	Vdc	6	--	7	--	9	8	--	--	16	
Low Threshold Voltage	V <sub>OLA</sub>	1 3	-1.080	--	-0.980	--	-0.910	--	Vdc	6	--	7	--	9	8	--	--	16	
Switching Time (50Ω Load)										+6.0 Vdc	Pulse In	Pulse Out		+7.0 Vdc	-3.2 Vdc			+2.0 Vdc	
Propagation Delay (+3.5 Vdc to 50%)	t <sub>g+1+</sub>	1	--	--	5.0	--	--	--	ns	7	6	1	--	9	8	--	--	16	
	t <sub>g1-</sub>	1	--	--	5.0	--	--	--	ns	6	7	1	--	9	8	--	--	16	
	t <sub>7+1+</sub>	1	--	--	5.0	--	--	--	ns	6	7	1	--	9	8	--	--	16	
	t <sub>7-1-</sub>	1	--	--	5.0	--	--	--	ns	6	7	1	--	9	8	--	--	16	
	t <sub>7+3-</sub>	3	--	--	5.0	--	--	--	ns	6	7	3	--	9	8	--	--	16	
	t <sub>7-3+</sub>	3	--	--	5.0	--	--	--	ns	6	7	3	--	9	8	--	--	16	
Rise Time (20% to 80%)	t <sub>1+</sub>	1	--	--	2.5	--	--	--	ns	6	7	1	--	9	8	--	--	16	
Fall Time (20% to 80%)	t <sub>1-</sub>	1	--	--	2.5	--	--	--	ns	6	7	1	--	9	8	--	--	16	

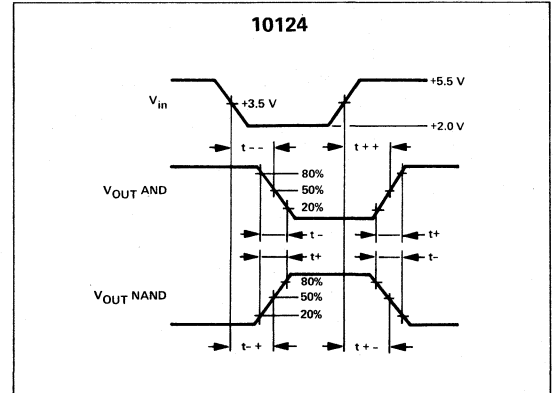
**NOTE:**

1 See switching time test circuit Propagation delay for this circuit is specified from +1.5 Vdc in to the 50% point on the output waveform. The +3.5 Vdc is shown here because all logic and supply levels are shifted 2 volts positive.

### SWITCHING TIME TEST CIRCUIT



### PROPAGATION DELAY WAVEFORMS @ 25°C



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 6 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10125 B,F: -30 to 85°C  
DIGITAL 10,000 SERIES ECL

### DESCRIPTION

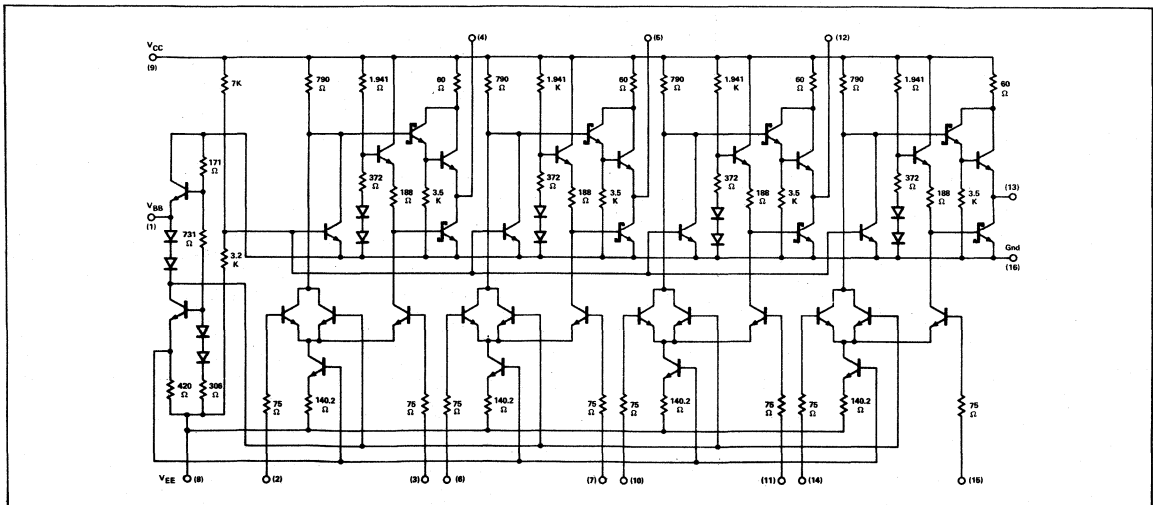
The 10125 is a quad differential translator. It can be used as a quad differential line receiver in a TTL system and also as a quad ECL to TTL translator. The 10125 incorporates differential inputs and Schottky-clamped TTL totem pole outputs. Differential inputs allow for use as an inverting/non-inverting translator or as a differential line receiver.

The outputs of the 10125 go to a low logic level whenever the inputs are left floating. The 10125 has fanout of 10 Schottky TTL loads. This device has an input common mode noise rejection of  $\pm 1.0$  Volt.

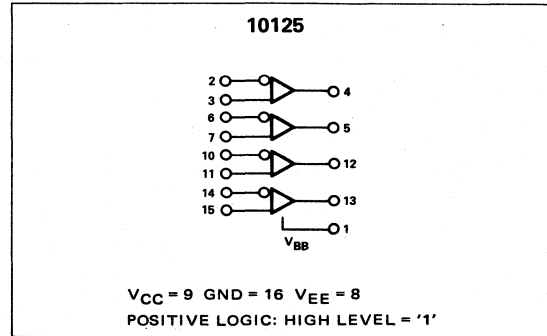
### FEATURES

- FAST PROPAGATION DELAY = 5.0ns TYP.
- POWER DISSIPATION = 360mW/PACKAGE TYPICAL
- DIFFERENTIAL INPUTS, ECL COMPATIBLE
- ECL 10,000 LEVEL  $V_{BB}$  AVAILABLE
- INVERTING OR NON-INVERTING FUNCTION
- SCHOTTKY TTL TOTEM POLE OUTPUTS
- RECOMMENDED POWER SUPPLIES:  
 $V_{CC} = +5.0V$  DC  $\pm 5\%$   
 $V_{EE} = -5.2V$  DC  $\pm 5\%$
- FOUR TRANSLATORS PER PACKAGE
- OUTPUT LEVELS SPECIFIED FOR INPUT VOLTAGE RANGE +0.2V to -2.2V

### CIRCUIT SCHEMATIC



### LOGIC DIAGRAM



### APPLICATIONS

- QUAD DIFFERENTIAL LINE RECEIVER
- QUAD ECL TO TTL TRANSLATOR
- QUAD MOS TO TTL SENSE AMP
- QUAD LEVEL DETECTOR

### TEMPERATURE RANGE

-30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin Cerdip
- B: 16-Pin Silicone Dip

ELECTRICAL CHARACTERISTICS

(at Listed Voltages and Ambient Temperatures).

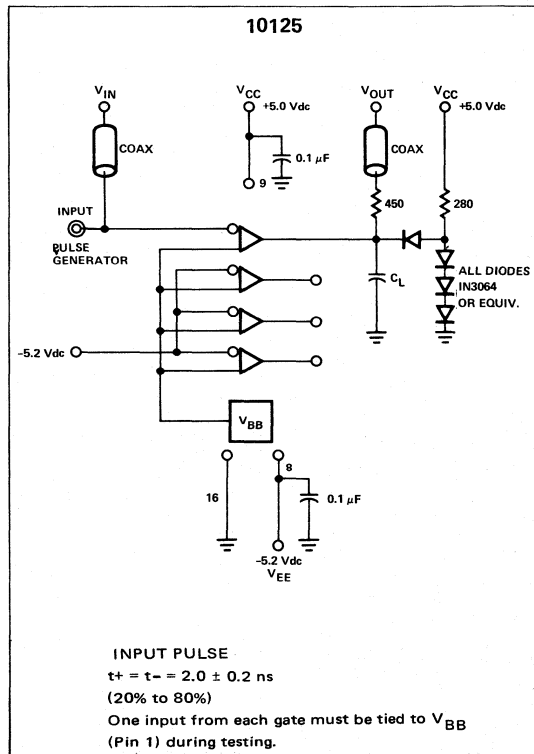
Temperature  
 -30°C  
 +25°C  
 +85°C

Characteristic	Symbol	Pin Under Test	TEST VOLTAGE VALUES												From Pin 1	V <sub>CC</sub>	V <sub>EE</sub>	Gnd	Output Condition				
			Volts																				
			V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>I LAmax</sub>	V <sub>IHH</sub>	V <sub>ILH</sub>	V <sub>IHL</sub>	V <sub>ILL</sub>	V <sub>BB</sub>	V <sub>CC</sub>	V <sub>EE</sub>										
Negative Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16		
Positive Power Supply Drain Current	I <sub>CCH</sub>	9	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16		
Input Current	I <sub>INM</sub>	1	2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16		
Input Leakage Current	I <sub>CBO</sub>	2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	2,6,8,10,14	16		
High Output Voltage	V <sub>OH</sub>	4	2,7	-	-	2,7	-	2,7	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-1.0 mA	
Low Output Voltage	V <sub>OL</sub>	4	-	0.5	-	0.5	-	0.5	-	0.5	-	-	-	-	-	-	-	3,7,11,15	9	8	16	20 mA	
High Threshold Voltage	V <sub>OH(A)</sub>	4	2,7	-	-	2,7	-	2,7	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-1.0 mA	
Low Threshold Voltage	V <sub>OL(A)</sub>	4	-	0.5	-	0.5	-	0.5	-	0.5	-	-	-	-	-	-	-	3,7,11,15	9	8	16	20 mA	
Indeterminate Input Protection Tests	V <sub>OL(S)</sub>	1	4	-	0.5	-	0.5	-	0.5	-	-	-	-	-	-	-	-	3,7,11,15	9	2,3,6,7,8	16	20 mA	
Short Circuit Current	I <sub>OS</sub>	4	-	-	-	40	100	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	4.16	
Reference Voltage	V <sub>BB</sub>	1	-1.420	-1.28	-1.350	-1.230	-1.295	-1.150	-	-	-	-	-	-	-	-	-	3,7,11,15	-	-	-	-	
Common Mode Rejection Tests	V <sub>OH</sub>	4	2,7	-	-	2,7	-	2,7	-	-	-	-	-	3	2	-	-	-	9	8	16	-1.0 mA	
	V <sub>OL</sub>	4	-	0.5	-	-	-	0.5	-	-	-	-	-	2	3	-	-	-	9	8	16	20 mA	
	V <sub>OL</sub>	4	-	0.5	-	-	-	0.5	-	-	-	-	-	2	3	-	-	-	9	8	16	20 mA	
Switching Times Propagation Delay (50% to +1.5 Vdc)	t <sub>6+5</sub>	5	-	-	-	5.0	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	t <sub>6-5+</sub>	5	-	-	-	5.0	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	t <sub>2+4-</sub>	4	-	-	-	5.0	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	t <sub>2+4+</sub>	4	-	-	-	7.0	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	t <sub>2-4+</sub>	4	-	-	-	5.0	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	t <sub>2-4-</sub>	4	-	-	-	7.0	-	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	Rise Time (+1.0 Vdc to 2.0 Vdc)	t <sub>4+</sub>	4	-	-	-	5.0	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-
	Fall Time (+1.0 Vdc to 2.0 Vdc)	t <sub>4-</sub>	4	-	-	-	5.0	-	-	-	-	-	-	-	-	-	-	-	3,7,11,15	9	8	16	-

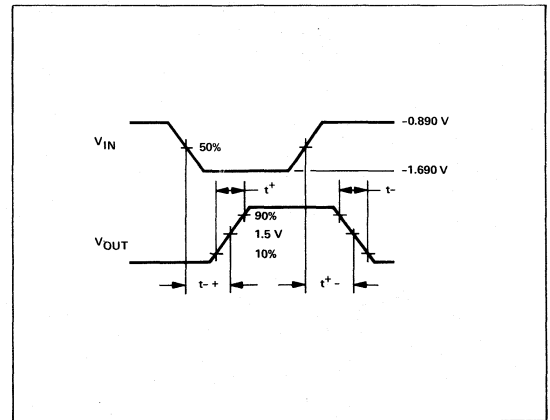
NOTES:

- 1 Individually test each input, apply V<sub>IHmax</sub> to pin under test.
- 2 C<sub>L</sub> includes test fixture

SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES:

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. The V<sub>BB</sub> level will shift approximately 5 mV with an air flow of 200 linear fpm.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope channel input.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10130F: -30 to +85°C, CERDIP

## DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10130 is a clocked dual D-type latch. Each latch may be clocked separately by holding the common clock in the low state, and using the clock enable inputs for the clocking function. If the common clock is to be used to clock the latch, the clock enable ( $\overline{CE}$ ) inputs must be in the low state. In this mode, the enable inputs perform the function of controlling the common clock ( $\overline{C}$ ).

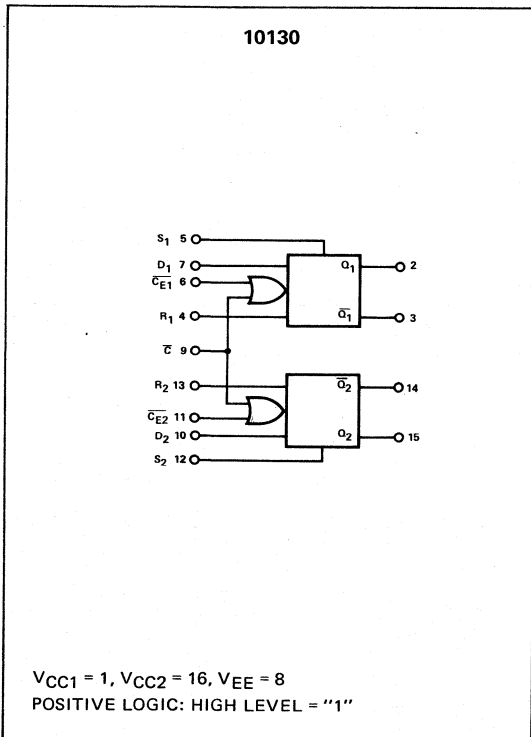
Any change at the D input will be reflected at the output while the clock is low. The outputs are latched on the positive transition of the clock. While the clock is in the high state, a change in the information present at the data inputs will not affect the output information.

Input pull-down resistors eliminate the need to tie unused inputs to  $V_{EE}$ .

The asynchronous set (S) and reset (R) inputs are effective only with the clock input high.

The 10130 is pin compatible with the 10131 dual master/slave type D flip-flop.

### LOGIC DIAGRAM



### FEATURES

- FAST PROPAGATION DELAY = 2.5 ns TYP (DATA)  
= 2.8 ns TYP (SET, RESET)  
= 3.0 ns TYP (CLOCK)
- LOW POWER DISSIPATION = 140 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE 50Ω LINES
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY
- PIN COMPATIBLE WITH 10131

### APPLICATIONS

- HIGH SPEED REGISTERS
- CONTROL LATCHES
- STATUS LATCHES

### TRUTH TABLE

D	C	S	R	$Q_{n+1}$
L	L	$\phi$	$\phi$	I
A	I	$\phi$	$\phi$	H
$\phi$	H	L	L	$Q_n$
$\phi$	H	H	L	H
$\phi$	H	L	H	L
$\phi$	H	H	H	N.D.

$C = \overline{CE} + \overline{C}$   
 $\phi$  = Don't care  
 N.D. = Not defined

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin CERDIP

**ELECTRICAL CHARACTERISTICS**  
(at Listed Voltages and Ambient Temperatures).

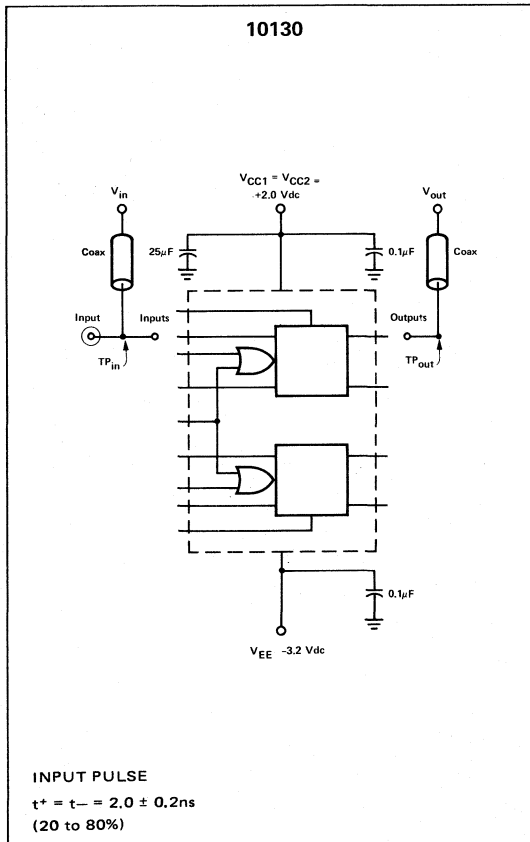
Characteristic	Symbol	Pin Under Test	10130 Test Limits						TEST VOLTAGE VALUES					Unit	V <sub>CC</sub> Gnd		
			-30° C		+25° C		+85° C		(Volts)								
			Min	Max	Min	Typ	Max	Min	Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VLA</sub> max			V <sub>EE</sub>	
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	28	35	—	—	mAdc	9	—	—	—	8	1,16	
Input Current	I <sub>inH</sub>	6,11	—	—	—	—	220	—	—	μAdc	6	—	—	—	8	1,16	
		9	—	—	—	—	205	—	—	—	4,0	—	—	—	—	—	
		4,5,7	—	—	—	—	285	—	—	—	5,9	—	—	—	—	—	
	I <sub>inL</sub>	4*	—	—	0.50	—	—	—	—	μAdc	—	4	—	—	8	1,16	
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	7	—	—	—	8	1,16	
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	—	7	—	—	8	1,16	
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.060	—	-0.980	—	—	-0.910	—	Vdc	7	—	—	9	8	1,16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	7	—	—	9	8	1,16
Switching Times (50 Ω load) (See Figure 1)											+1.11 V		Pulse In	Pulse Out	-3.2 V	+2.0 V	
Propagation Delay	t <sub>7-2-</sub>	2	—	—	1.5	2.5	4.3	—	—	ns	—	—	7	2	8	1,16	
	t <sub>7+2+</sub>		—	—	1.5	2.5	4.3	—	—	—	—	—	7	—	—	—	
	t <sub>5+2+</sub>		—	—	1.5	2.8	4.3	—	—	—	6	—	5	—	—	—	
	t <sub>4+2-</sub>		—	—	1.2	2.8	4.3	—	—	—	6	—	4	—	—	—	
Rise Time (20% to 80%)	t <sub>2+</sub>		—	—	1.1	2.5	4.5	—	—	—	—	—	7	—	—	—	
Fall Time (20% to 80%)	t <sub>2-</sub>		—	—	1.1	2.5	4.5	—	—	—	—	—	7	—	—	—	
Setup Time	t <sub>setup</sub> †	2	—	—	—	—	2.5	—	—	ns	—	—	6,7	2	8	1,16	
Hold Time	t <sub>hold</sub> ††	2	—	—	1.5	—	—	—	—	ns	—	—	6,7	2	8	1,16	

\* All other inputs are tested in the same manner.

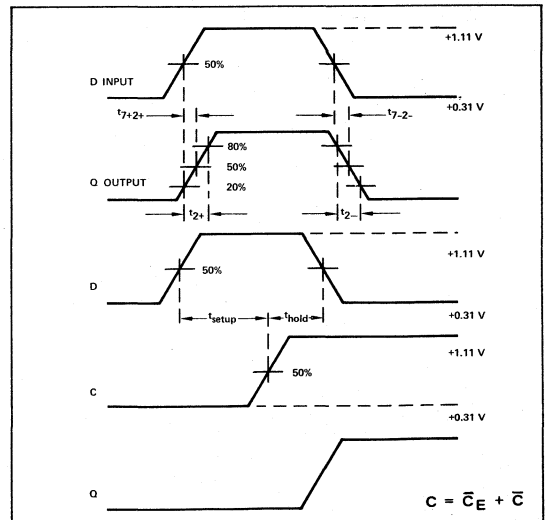
† t<sub>setup</sub> is the minimum time before the positive transition of the clock pulse (C) that information must be present at the data input (D).

†† t<sub>hold</sub> is the minimum time after the positive transition of the clock pulse (C) that information must remain unchanged at the data input (D).

**SWITCHING TIME TEST CIRCUIT**



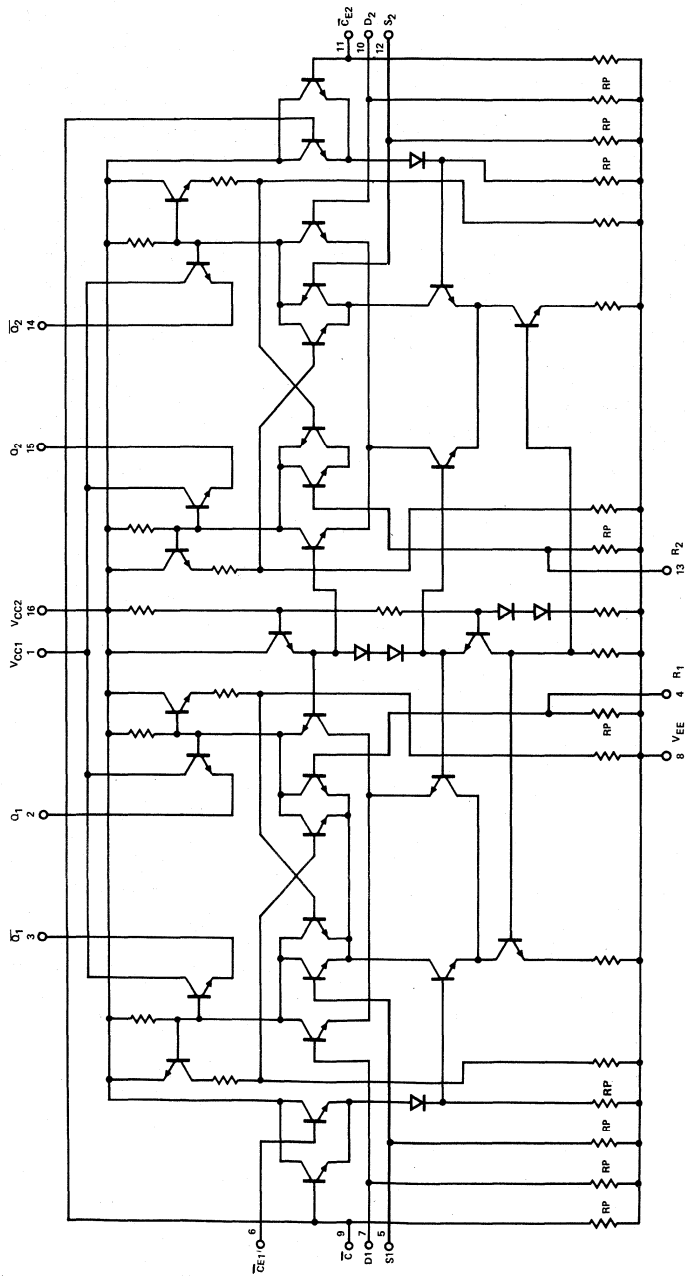
**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10130



C = C<sub>E</sub> + C<sub>i</sub> All RP = 50 kΩ.

10131F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

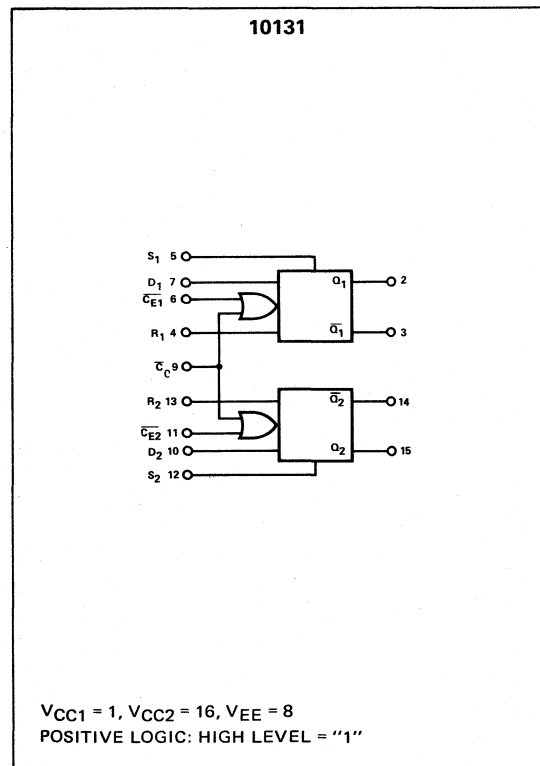
## DESCRIPTION

The 10131 is a dual master-slave type D flip-flop. Asynchronous set (S) and reset (R) override clock ( $\bar{C}$ ) and clock enable ( $\bar{CE}$ ) inputs. Each flip-flop may be clocked separately by holding the common clock in the low state and using the enable inputs for the clocking function. If the common clock is to be used to clock the flip-flop, the clock enable inputs must be in the low state. In this case, the enable inputs perform the function of controlling the common clock.

The output states of the flip-flop change on the positive transition of the clock. A change in the information present at the data (D) input will not affect the output information at any other time due to master-slave construction. Input pull-down resistors eliminate the need to tie unused inputs to  $V_{EE}$ . Output rise and fall times have been optimized to provide relaxation of system design and layout criteria.

The 10131 is pin compatible with the 10130 dual D-type latch.

## LOGIC DIAGRAM



## FEATURES

- $f_{TOG} = 125 \text{ MHz MIN}$   
= 160 MHz TYP
- FAST PROPAGATION DELAY  
= 2.8 ns TYP (SET, RESET)  
= 3.0 ns TYP (CLOCK)
- LOW POWER DISSIPATION = 235 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY  
- CAN DRIVE 50  $\Omega$  LINES
- HIGH Z INPUTS - INTERNAL 50 k $\Omega$  PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 \text{ V} \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY
- PIN COMPATIBLE WITH 10130

## APPLICATIONS

- CONTROL LOGIC
- STATUS LOGIC
- COUNTERS
- SHIFT REGISTER
- PRESCALERS

## TRUTH TABLE

D	C*	S	R	$Q_{n+1}$
$\phi$	L	L	L	$Q_n$
L	H	L	L	L
H	H	L	L	H
$\phi$	$\phi$	H	L	H
$\phi$	$\phi$	L	H	L
$\phi$	$\phi$	H	H	N.D.

\* An H represents a transition from L to H between  $t = n$  and  $t = n + 1$

$C = C_C + \bar{CE}$

N.D. = Not defined

## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- F: 16-Pin CERDIP

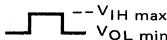


**ELECTRICAL CHARACTERISTICS**  
(at Listed Voltages and Ambient Temperatures).

Characteristic	Symbol	Pin Under Test	10131 Test Limits								Unit	TEST VOLTAGE VALUES					(V <sub>CC</sub> ) Gnd
			-30°C		+25°C		+85°C		V <sub>dC</sub> ± 1%								
			Min	Max	Min	Typ	Max	Min	Max	V <sub>IH</sub> max		V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>		
			VOLTAGE APPLIED TO PINS LISTED BELOW:									V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>	
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	45	56	—	—	mAdc	9	—	—	—	8	1,16	
Input Current	I <sub>inH</sub>	4	—	—	—	—	330	—	—	μAdc	4	—	—	—	8	1,16	
		5	—	—	—	—	330	—	—	μAdc	5	—	—	—	8	1,16	
		6	—	—	—	—	220	—	—	μAdc	6	—	—	—	8	1,16	
		7	—	—	—	—	245	—	—	μAdc	7	—	—	—	8	1,16	
		9	—	—	—	—	265	—	—	μAdc	9	—	—	—	8	1,16	
Input Leakage Current	I <sub>inL</sub>	4,5,*	—	—	0.5	—	—	—	—	μAdc	—	*	—	—	8	1,16	
		6,7,9	—	—	0.5	—	—	—	—	μAdc	—	*	—	—	8	1,16	
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	5	—	—	—	8	1,16	
		2†	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	7	—	—	—	8	1,16	
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	5	—	—	—	8	1,16	
		3†	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	7	—	—	—	8	1,16	
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	5	—	8	1,16	
		3†	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	7	9	8	1,16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	5	—	8	1,16	
		3†	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	7	9	8	1,16	
Switching Times Clock Input**											+1.1 Vdc	Pulse In	Pulse Out	-3.2 Vdc	+2.0 Vdc		
Propagation Delay	t <sub>p+</sub> 2-	2	1.4	4.6	1.5	3.0	4.5	1.5	5.0	ns	—	—	9	2	8	1,16	
		t <sub>p+</sub> 2+	2	↓	↓	↓	↓	↓	↓	↓	ns	7	—	9	2	8	1,16
		t <sub>p+</sub> 2+	2	↓	↓	↓	↓	↓	↓	↓	ns	7	—	6	2	8	1,16
		t <sub>p+</sub> 2-	2	↓	↓	↓	↓	↓	↓	↓	ns	—	—	6	2	8	1,16
		t <sub>p+</sub> 2-	2	↓	↓	↓	↓	↓	↓	↓	ns	—	—	6	2	8	1,16
Rise Time (20% to 80%)	t <sub>2+</sub>	2	0.8	—	1.1	2.5	—	1.1	4.9	ns	7	—	9	2	8	1,16	
		t <sub>2-</sub>	2	0.8	—	1.1	2.5	—	1.1	4.9	ns	—	—	9	2	8	1,16
Set Input Propagation Delay	t <sub>5+</sub> 2+	15	1.1	4.4	1.2	2.8	4.3	1.2	4.8	ns	—	—	5	2	8	1,16	
		t <sub>12+</sub> 15+	2	↓	↓	↓	↓	↓	↓	↓	ns	—	—	12	15	8	1,16
		t <sub>5+</sub> 3-	3	↓	↓	↓	↓	↓	↓	↓	ns	—	—	5	3	8	1,16
		t <sub>12+</sub> 14-	14	↓	↓	↓	↓	↓	↓	↓	ns	—	—	12	14	8	1,16
Reset Input Propagation Delay	t <sub>4+</sub> 2-	2	1.1	4.4	1.2	2.8	4.3	1.2	4.8	ns	—	—	4	2	8	1,16	
		t <sub>13+</sub> 15-	15	↓	↓	↓	↓	↓	↓	↓	ns	—	—	13	15	8	1,16
		t <sub>4+</sub> 3+	3	↓	↓	↓	↓	↓	↓	↓	ns	—	—	4	3	8	1,16
		t <sub>13+</sub> 14+	14	↓	↓	↓	↓	↓	↓	↓	ns	—	—	13	14	8	1,16
Setup Time	t <sub>setup</sub>	7	—	—	1.5	2.5	—	—	—	ns	—	—	6,7	2	8	1,16	
Hold Time	t <sub>hold</sub>	7	—	—	1.5	—	—	—	—	ns	—	—	6,7	2	8	1,16	
Toggle Frequency (Max)	f <sub>Tog</sub>	2	125	—	125	160	—	125	—	MHz	—	—	6	2	8	1,16	

\* Individually test each input; apply V<sub>IL</sub> min to pin under test.

\*\* Pin 3 is tied to pin 7 for these tests.

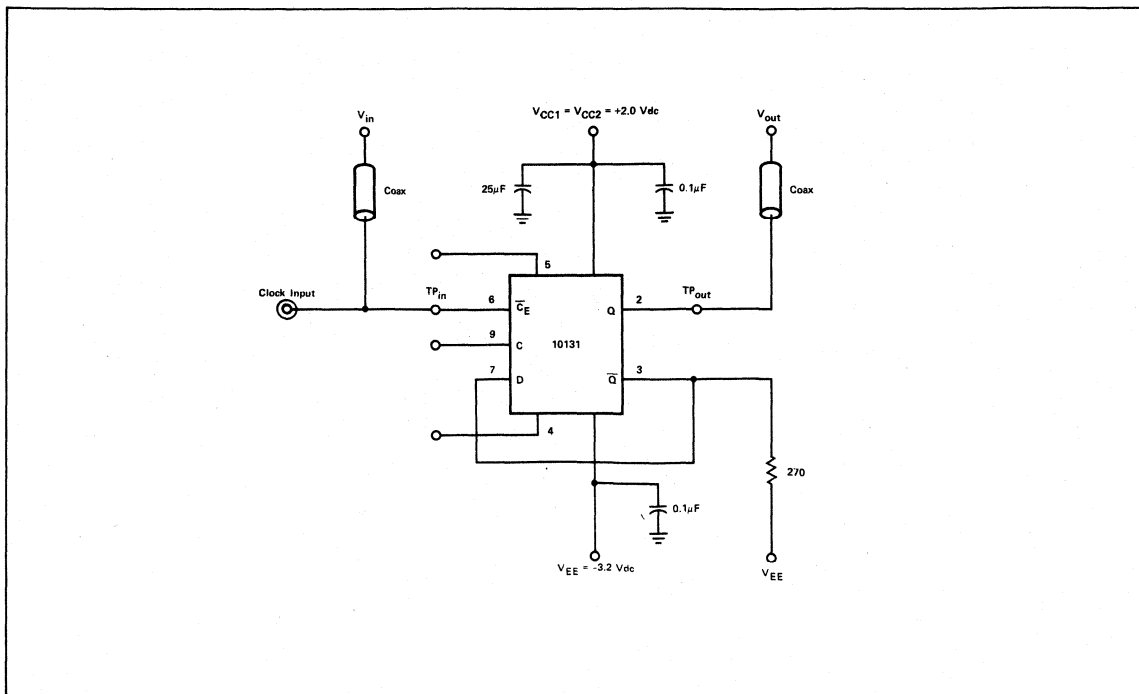
† Output level to be measured after a clock pulse has been applied to the C<sub>E</sub> input (pin 6) 

**NOTES:**

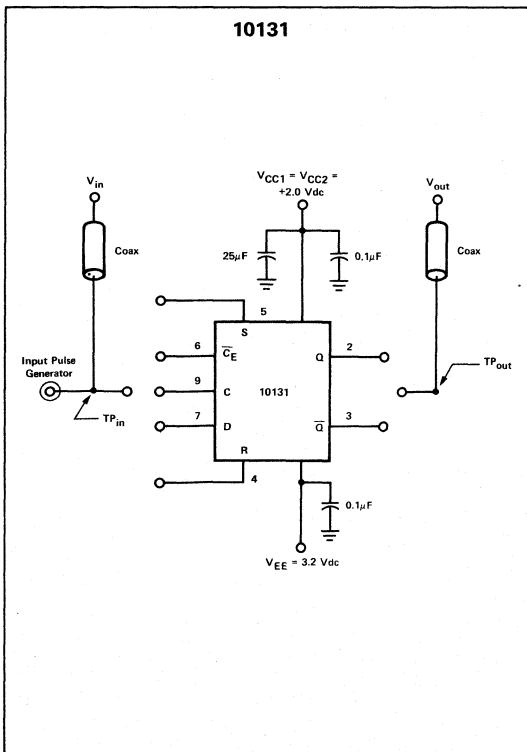
1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.

- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

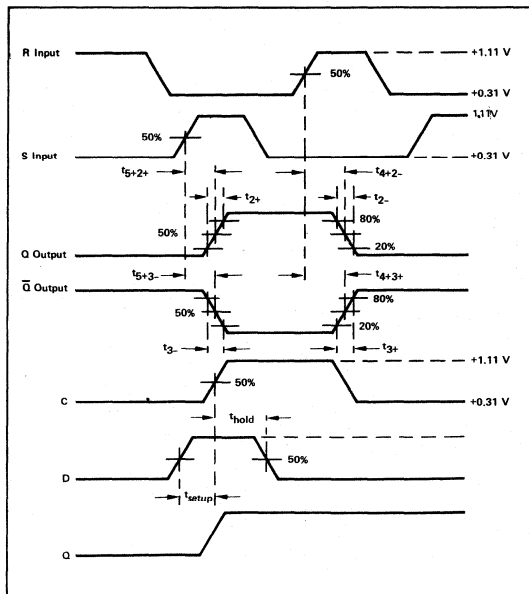
TOGGLE FREQUENCY TEST CIRCUIT



SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C

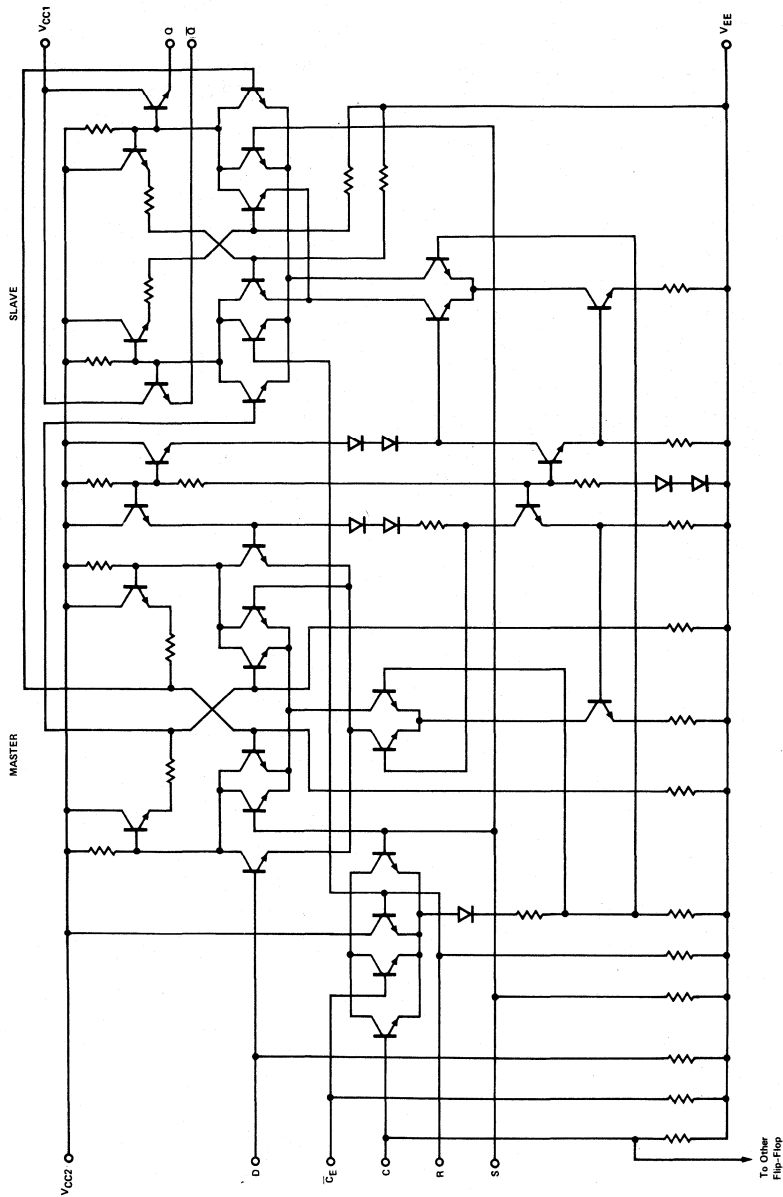


NOTE  
 $t_{setup}$  is the minimum time before the positive transition of the clock pulse (C) that information must be present at the data input (D).

$t_{hold}$  is the minimum time after the positive transition of the clock pulse (C) that information must remain unchanged at the data input (D).

CIRCUIT SCHEMATIC

10131  
(1/2 OF CIRCUIT SHOWN)



10132F: -30 TO +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

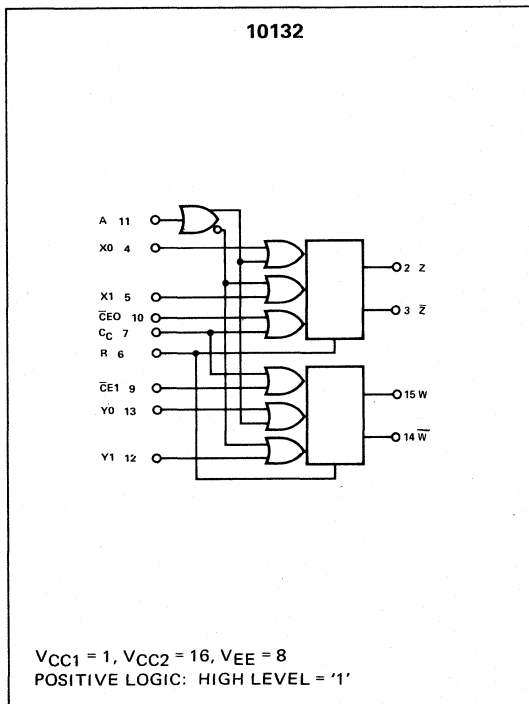
The 10132 is a dual clocked D-type latch with 2 to 1 data multiplexing. Each latch may be clocked separately by holding the common clock in the low state, and using the clock enable inputs for the clocking function. If the common clock is to be used to clock the latch, the clock enable ( $\overline{CE}$ ) inputs must be in the low state. In this state, the enable inputs perform the function of enabling the common clock, ( $C_C$ ).

Any change at the selected D input will be reflected at the output while the clock is low. The outputs are latched on the positive transition of the clock. While the clock is in the high state, a change in the information present at the data or select inputs will not affect the output information.

The asynchronous reset input (R) overrides the clock inputs.

Input pull-down resistors eliminate the need to tie unused inputs to  $V_{EE}$ .

### LOGIC DIAGRAM



### FEATURES

- HIGH SPEED COMBINED MULTIPLEXER – LATCH IMPROVES SYSTEM PERFORMANCE.
- MULTIPLEXED INPUTS TO REDUCE PACKAGE COUNT
- FAST PROPAGATION DELAY = 2.5 ns TYP (DATA)  
= 3.7 ns TYP (SELECT)  
= 3.0 ns TYP (RESET)  
= 4.0 ns TYP (CLOCK)
- LOW POWER DISSIPATION = 200 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE 50  $\Omega$  LINES
- HIGH Z INPUTS – INTERNAL 50 k $\Omega$  PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

### APPLICATIONS

- COMBINED MULTIPLEXER – REGISTER FOR:
  - high speed central processors
  - high speed peripherals
  - high speed minicomputers
  - high speed accumulators
  - communication systems

### TRUTH TABLE

R	$X_{in}$	$C_C$	$\overline{CE}$	$Z_{n+1}$
L	L	L	L	L
L	L	L	H	$Z_n$
L	L	H	L	$Z_n$
L	L	H	H	$Z_n$
L	H	L	L	H
L	H	L	H	$Z_n$
L	H	H	L	$Z_n$
L	H	H	H	$Z_n$
H	$\phi$	H	$\phi$	L

$\phi$  = Don't Care.

$$X_{in} = \overline{A} \cdot X_0 + A \cdot X_1$$

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

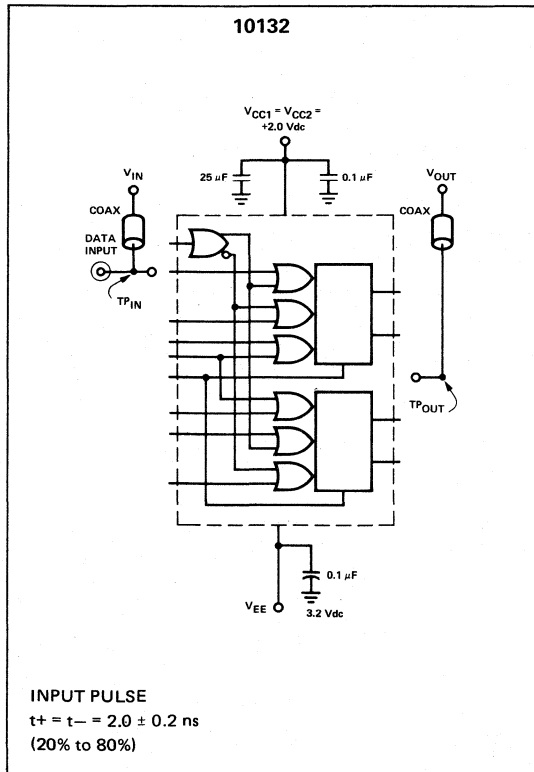
- F: 16-Pin CERDIP

**ELECTRICAL CHARACTERISTICS**  
(at Listed Voltages and Ambient Temperatures).

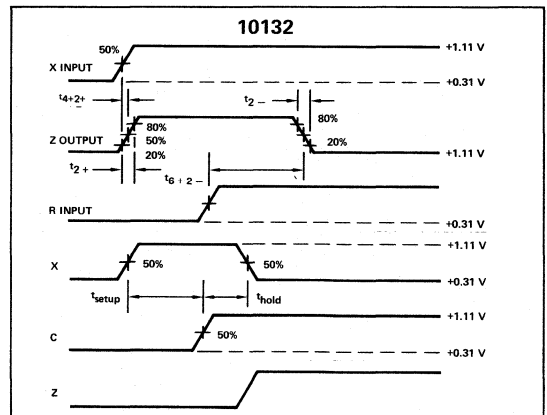
Characteristic	Symbol	Pin Under Test	10132 Test Limits										TEST VOLTAGE VALUES (Volts)					Gnd
			-30° C		+25° C		+85° C		Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>				
			Min	Max	Min	Max	Min	Max										
Power Supply Current	I <sub>E</sub>	8	-	-	-	-	50	-	-	-	-	mAdc	7,11	-	-	-	8	1,16
Input Current	I <sub>in</sub> H	4	-	-	-	-	290	-	-	-	-	μAdc	4	-	-	-	8	1,16
		5	-	-	-	-	290	-	-	-	-	μAdc	5,11	-	-	-	8	1,16
		6	-	-	-	-	390	-	-	-	-	μAdc	6,7	-	-	-	8	1,16
		7	-	-	-	-	290	-	-	-	-	μAdc	7	-	-	-	8	1,16
		10	-	-	-	-	220	-	-	-	-	μAdc	10	-	-	-	8	1,16
		11	-	-	-	220	-	-	-	-	μAdc	11	-	-	-	8	1,16	
		4*	-	-	0.50	-	-	-	-	-	-	μAdc	-	4	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	-	-	Vdc	4	7,9,10	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	-	-	Vdc	4	7,9,11	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	-	-	Vdc	-	7,9,10	4	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	3	-	-1.655	-	-	-1.630	-	-1.595	-	-	Vdc	-	7,9,10	4	-	8	1,16
Switching Times (50-ohm load) (See Figure 1)													+1.11 V	+0.31 V	Pulse In	Pulse Out	-3.2 V	+2.0 V
Propagation Delay	Data	t <sub>4+2+</sub>	-	-	-	2.5	-	-	-	-	ns	-	7,9,10	4	2	8	1,16	
	Reset	t <sub>6+2-</sub>	-	-	-	3.0	-	-	-	-	ns	-	7	6	8	1,16		
	Clock	t <sub>7-2+</sub>	-	-	-	4.0	-	-	-	-	ns	-	4	7	8	1,16		
	Select	t <sub>11+2+</sub>	-	-	-	3.7	-	-	-	-	ns	-	5	7	11	8	1,16	
Setup Time	Data	t <sub>setup</sub>	2	-	-	1.5	-	-	-	-	ns	-	11	4,10	2	8	1,16	
	Select	t <sub>setup</sub>	2	-	-	2.5	-	-	-	-	ns	-	5	7	10,11	2	8	1,16
Hold Time	Data	t <sub>hold</sub>	2	-	-	0.0	-	-	-	-	ns	-	11	4,10	2	8	1,16	
	Select	t <sub>hold</sub>	2	-	-	-0.5	-	-	-	-	ns	-	5	7	10,11	2	8	1,16
Rise Time (20% to 80%)		t <sub>2+</sub>	2	-	-	2.0	-	-	-	-	ns	-	7,9,10	4	2	8	1,16	
Fall Time (20% to 80%)		t <sub>2-</sub>	2	-	-	2.0	-	-	-	-	ns	-	7,9,10	4	2	8	1,16	

\*All other inputs tested in the same manner.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10133F: -30 to +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

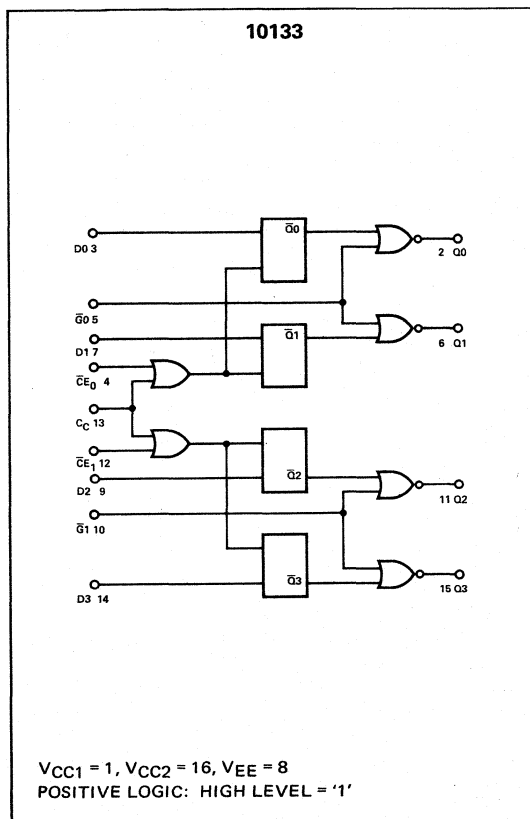
### ADVANCED INFORMATION

#### DESCRIPTION

The 10133 is a high speed, low power, ECL quad latch consisting of four bistable latch circuits with D-type inputs and gated Q outputs. Open emitters allow a large number of outputs to be wire-ORed together. Latch outputs are gated, allowing direct wiring to a bus. When the clock is high, the outputs will follow the D inputs. Information is latched on the negative going transition of the clock.

The outputs are gated low when the output enable is high. All four latches may be clocked at one time with the common clock, or each half may be clocked separately with its clock.

#### LOGIC DIAGRAM



#### TEMPERATURE RANGE

- 30 to +85°C Operating Ambient

#### PACKAGE TYPE

- F: 16-Pin CERDIP

5-78

#### FEATURES

- FAST PROPAGATION DELAY
  - = 4.0 ns TYP CLOCK OR DATA TO OUTPUT
  - = 2.0 ns TYP ENABLE TO OUTPUT
  - = 0.7 ns TYP SETUP AND HOLD TIMES
- GATED OUTPUTS FOR BUS-ORIENTED APPLICATIONS
- HIGH DENSITY - FOUR LATCHES PLUS GATING
- LOW POWER DISSIPATION = 290 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY - CAN DRIVE FOUR 50 Ω LINES
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: VEE = -5.2 V ±5% RECOMMENDED
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

#### APPLICATIONS

- TEMPORARY STORAGE ELEMENT IN:
  - high speed central processors
  - high speed peripherals and memories
  - high speed digital communications instrumentation
  - test equipment
- BUS-ORIENTED STORAGE REGISTER FOR:
  - mini-computers
  - array processors

#### TRUTH TABLE

$\bar{G}$	C	D	$Q_{n+1}$
H	$\phi$	$\phi$	L
L	L	$\phi$	$Q_n$
L	H	L	L
L	H	H	H

$$C = \bar{C}_C + C_E$$

$\phi$  = Don't Care

#### NOTES:

- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.

# SIGNETICS QUAD D-TYPE LATCH (WITH GATED OUTPUTS) ■ 10133

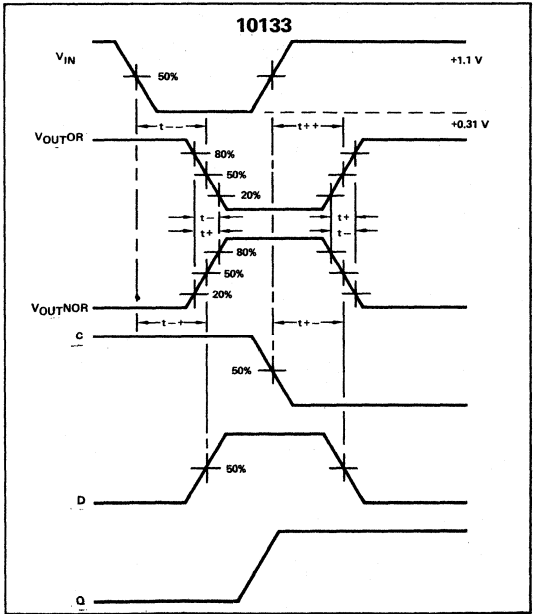
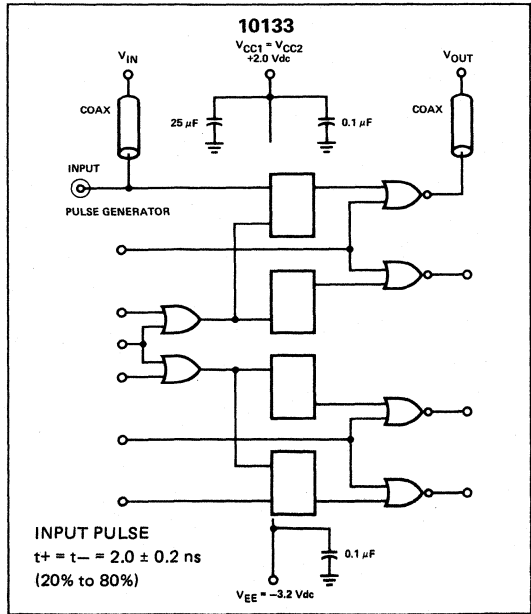
(at Listed Voltages and Ambient Temperatures).

TEST VOLTAGE VALUES					
(Volts)					
@ Test Temperature	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>
-30° C	-0.890	-1.890	-1.205	-1.500	-5.2
+25° C	-0.810	-1.850	-1.105	-1.475	-5.2
+85° C	-0.700	-1.825	-1.035	-1.440	-5.2

Characteristic	Symbol	Pin Under Test	10133 Test Limits						TEST VOLTAGE APPLIED TO PINS LISTED BELOW:							
			-30° C		+25° C		+85° C		Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>	Gnd	
			Min	Max	Min	Typ	Max	Min								Max
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	-	75	-	-	mAdc	-	13	-	-	8	1,16
Input Current	I <sub>inH</sub>	3	-	-	-	-	245	-	-	μAdc	3	-	-	-	8	1,16
		4	-	-	-	-	220	-	-	μAdc	4	-	-	-	8	1,16
		5	-	-	-	-	350	-	-	μAdc	5	-	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	3	-	-	0.5	-	-	-	-	μAdc	-	3	-	-	8	1,16
		2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	3,4	-	-	-	8	1,16
		2	↓	↓	↓	-	↓	↓	↓	Vdc	3,13	-	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	13	-	-	-	8	1,16
		2	↓	↓	↓	-	↓	↓	↓	Vdc	3,5	-	-	-	8	1,16
		2	↓	↓	↓	-	↓	↓	↓	Vdc	13	-	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	3,4	-	-	5	8	1,16
		2	↓	-	↓	-	↓	↓	↓	Vdc	4	-	3	-	8	1,16
		2	↓	-	↓	-	↓	↓	↓	Vdc	3,4	-	-	-	8	1,16
		2†	↓	-	↓	-	↓	↓	↓	Vdc	3	-	-	-	8	1,16
		2††	↓	-	↓	-	↓	↓	↓	Vdc	3	-	-	-	8	1,16
		2††	↓	-	↓	-	↓	↓	↓	Vdc	3	-	4	-	8	1,16
		2	↓	-	↓	-	↓	↓	↓	Vdc	3	-	13	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	-	-1.655	-	-	-1.630	-	-1.595	Vdc	3,4	-	5	-	8	1,16
		2	-	↓	-	-	↓	↓	↓	Vdc	4	-	3	-	8	1,16
		2	-	↓	-	-	↓	↓	↓	Vdc	4	-	-	-	8	1,16
		2†	-	↓	-	-	↓	↓	↓	Vdc	3	-	-	-	8	1,16
		2††	-	↓	-	-	↓	↓	↓	Vdc	3	-	13	-	8	1,16
Switching Times ††† (50 Ω load)	Propagation Delay	13+2+	-	-	-	4.0	-	-	-	ns	+1.11 V	-	Pulse In	Pulse Out	-3.2 V	+2.0 V
		14+2+	-	-	-	4.0	-	-	-	ns	4	-	3	2	8	1,16
		15-2+	-	-	-	2.0	-	-	-	ns	3	-	4	2	8	1,16
		1setup*	-	-	-	0.7	-	-	-	ns	-	-	5	2	8	1,16
		1hold**	-	-	-	0.7	-	-	-	ns	-	-	3	2	8	1,16
		12+	-	-	-	2.0	-	-	-	ns	4	-	3	2	8	1,16
		12-	-	-	-	2.5	-	-	-	ns	4	-	3	2	8	1,16

† Output level to be measured after a clock pulse has been applied to the clock input (Pin 4).  
 †† Data input at proper high/low level while clock pulse is high so that device latches at proper high/low level for test. Levels are measured after device has latched.

\*<sub>setup</sub> is minimum time before the negative transition of the clock pulse (C) that information must be present at the data input (D).  
 \*\*<sub>hold</sub> is the minimum time after the negative transition of the clock pulse (C) that information must remain unchanged at the data input (D).



10134F: -30 to +85°C CERDIP

DIGITAL 10,000 SERIES ECL

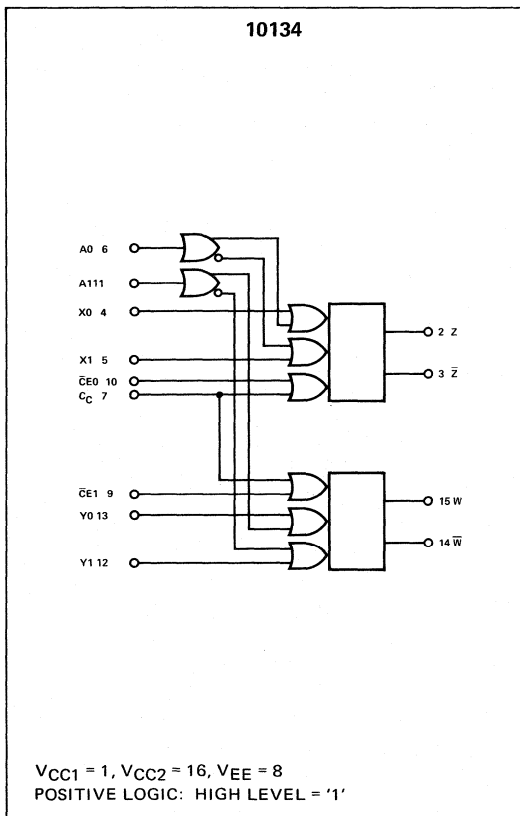
### DESCRIPTION

The 10134 is a dual clocked D-type latch with 2 to 1 data multiplexing. Each latch may be clocked separately by holding the common clock in the low state, and using the clock enable inputs for the clocking function. If the common clock is to be used to clock the latch, the clock enable ( $\overline{CE}$ ) inputs must be in the low state. In this state, the enable inputs perform the function of enabling the common clock ( $C_C$ ).

Any change at the selected D input will be reflected at the output while the clock is low. The outputs are latched on the positive transition of the clock. While the clock is in the high state, a change in the information present at the data or select inputs will not affect the output information.

Input pull-down resistors eliminate the need to tie unused inputs to  $V_{EE}$ .

### LOGIC DIAGRAM



### FEATURES

- HIGH SPEED COMBINED MULTIPLEXER - LATCH IMPROVES SYSTEM PERFORMANCE.
- MULTIPLEXED INPUTS TO REDUCE PACKAGE COUNT
- FAST PROPAGATION DELAY = 2.5 ns TYP (DATA) = 3.5 ns TYP (SELECT) = 4.0 ns TYP (CLOCK)
- LOW POWER DISSIPATION = 225 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY - CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

### APPLICATIONS

- COMBINED MULTIPLEXER - REGISTER FOR:
  - high speed central processors
  - high speed peripherals
  - high speed minicomputers
  - high speed accumulators
  - communication systems

### TRUTH TABLE

C	A0	X0	X1	$Z_{n+1}$
L	L	L	$\phi$	L
L	L	H	$\phi$	H
L	H	$\phi$	L	L
L	H	$\phi$	H	H
H	$\phi$	$\phi$	$\phi$	$Z_n$

$\phi$  - Don't Care

$C = \overline{CE} + C_C$

$X_{in} = A0 \cdot X0 + A0 \cdot X1$

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin CERDIP



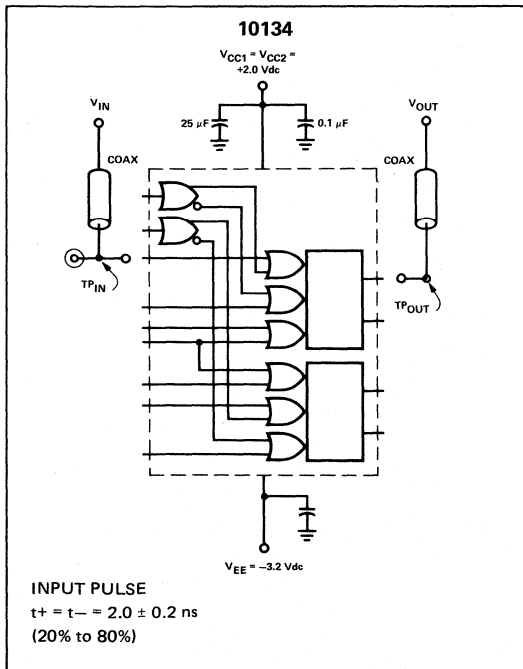
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

Characteristic	Symbol	Pin Under Test	10134 Test Limits						Unit	TEST VOLTAGE VALUES (Volts)					Gnd
			-30° C		+25° C		+85° C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>	
			Min	Max	Min	Max	Min	Max							
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	55	—	—	mAdc	6,7,11	—	—	—	8	1,16
Input Current	I <sub>in</sub> H	4	—	—	—	290	—	—	μAdc	4	—	—	—	8	1,16
		5	—	—	—	290	—	—		5,6	—	—	—	8	1,16
		6	—	—	—	220	—	—		6	—	—	—	8	1,16
		7	—	—	—	290	—	—		7	—	—	—	8	1,16
		10	—	—	—	220	—	—		10	—	—	—	8	1,16
	I <sub>in</sub> L	4*	—	—	0.50	—	—	—	μAdc	—	4	—	—	8	1,16
Logic "1"	V <sub>OH</sub>	2	-1.080	-0.890	-0.960	-0.810	-0.890	-0.700	Vdc	4	6,7,10	—	—	8	1,16
Output Voltage		2	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700	Vdc	5,6	7,10	—	—	8	1,16
Logic "0"	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	—	4,6,7,10	—	—	8	1,16
Output Voltage		2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	6	5,7,10	—	—	8	1,16
Logic "1"	V <sub>OHA</sub>	2	-1.080	—	-0.980	—	-0.910	—	Vdc	—	6,7,10	4	—	8	1,16
Threshold Voltage		2	-1.080	—	-0.980	—	-0.910	—	Vdc	6	7,10	5	—	8	1,16
Logic "0"	V <sub>OLA</sub>	2	—	-1.655	—	-1.630	—	-1.595	Vdc	—	6,7,10	—	4	8	1,16
Threshold Voltage		2	—	-1.655	—	-1.630	—	-1.595	Vdc	6	7,10	—	5	8	1,16
Switching Times (50-ohm load) (See Figure 1)					Typ	Max				+1.11 V	+0.31 V	Pulse In	Pulse Out	-3.2 V	+2.0 V
Propagation Delay	Data	t <sub>4+2+</sub>	2	—	—	2.5	—	—	ns	—	6,7,10	4	2	8	1,16
	Clock	t <sub>10-2+</sub>	2	—	—	4.0	—	—	ns	4	7	10	2	8	1,16
	Select	t <sub>6+2+</sub>	2	—	—	3.5	—	—	ns	5	7,10	6	2	8	1,16
Setup Time	Data	t <sub>setup</sub>	2	—	—	1.5	—	—	ns	—	6,7	4,10	2	8	1,16
	Select	t <sub>setup</sub>	2	—	—	2.5	—	—	ns	5	7,11	6,10	2	8	1,16
Hold Time	Data	t <sub>hold</sub>	2	—	—	0.0	—	—	ns	—	6,7	4,10	2	8	1,16
	Select	t <sub>hold</sub>	2	—	—	-0.5	—	—	ns	5	7,11	6,10	2	8	1,16
Rise Time (20% to 80%)	Data	t <sub>2+</sub>	2	—	—	2.0	—	—	ns	—	6,7,10	4	2	8	1,16
Fall Time (20% to 80%)	Select	t <sub>2-</sub>	2	—	—	2.0	—	—	ns	—	6,7,10	4	2	8	1,16

\*All other inputs tested in the same manner.

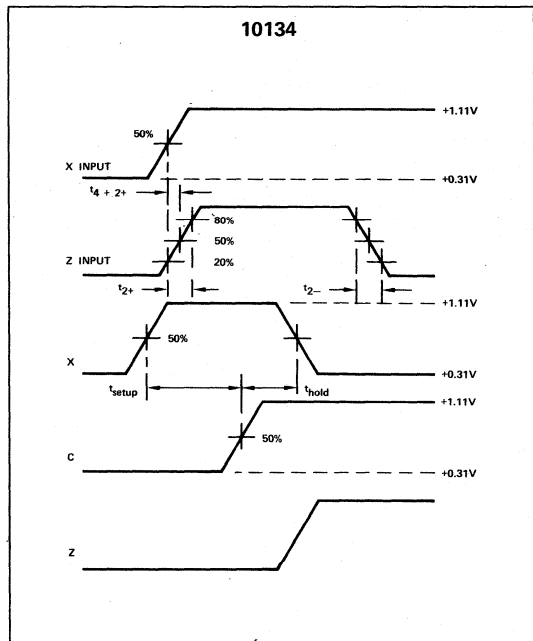
**SWITCHING TIME TEST CIRCUIT**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.

**PROPAGATION DELAY WAVEFORMS @ 25° C**



- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10135F: -30 to 85°C

DIGITAL 10,000 ECL

## DESCRIPTION

The 10135 is a dual master-slave dc coupled J-K flip-flop. Asynchronous set (S) and reset (R) are provided. The set and reset inputs override the clock. Complementary outputs are provided for driving twisted pair cable and to minimize package count by eliminating the need for inverters.

The output states of the flip-flop change on the positive transition of the clock.

Input pulldown resistors eliminate the need to tie unused inputs to  $V_{EE}$ .

## FEATURES

- $f_{TOG} = 140\text{MHz TYP}$
- FAST PROPAGATION DELAY  
= 3.0ns TYP (SET, RESET)  
= 3.0ns TYP (CLOCK)
- LOW POWER DISSIPATION = 235mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY - CAN DRIVE 50Ω LINES
- HIGH Z INPUTS - INTERNAL 50kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

## APPLICATIONS

CONTROL LOGIC  
STATUS LOGIC  
COUNTERS  
SHIFT REGISTER

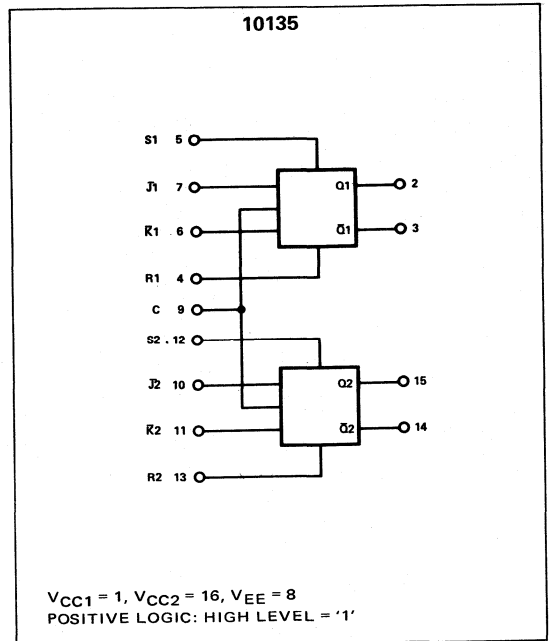
## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

## PACKAGE TYPE

F: 16-Pin CERDIP  
5-82

## LOGIC DIAGRAM



## R-S TRUTH TABLE

R	S	$Q_{n+1}$
L	L	$Q_n$
L	H	H
H	L	L
H	H	N.D.

N.D. = Not Defined

## CLOCK J-K TRUTH TABLE\*

J	$\bar{K}$	$\bar{Q}_{n+1}$
L	L	$Q_n$
H	L	L
L	H	H
H	H	$Q_n$

\*Output states change on positive transition of clock for J-K input condition present.

**ELECTRICAL CHARACTERISTICS**  
At Listed Voltages and Ambient Temperatures

Characteristic	Symbol	Pin Under Test	10135 Test Limits										TEST VOLTAGE VALUES					Gnd
			-30°C			+25°C			+85°C			V <sub>dc</sub> ± 1%						
			Min	Max	Unit	Min	Typ	Max	Min	Max	Unit	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IILA</sub> max	V <sub>EE</sub>		
			VOLTAGE APPLIED TO PINS LISTED BELOW:															
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	45	57	-	-	mAdc	-	-	-	-	8	1.16		
Input Current	I <sub>in H</sub>	6,7,9,10,11 4,5,12,13	-	-	-	-	265	-	-	μAdc	1	-	-	-	8	1.16		
Input Leakage Current	I <sub>in L</sub>	4,5,6,7,9, 10,11,12,13	-	-	0.5	-	-	-	-	μAdc	1	2	-	-	8	1.16		
Logic "1" Output Voltage	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	5	-	-	-	8	1.16		
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	6	-	-	-	8	1.16		
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	5	-	8	1.16		
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	6	-	-	-	8	1.16		
Switching Times																		
Clock Input																		
Propagation Delay	t <sub>g+2+</sub>	2	-	-	1.0	3.0	4.5	-	-	ns	-	-	9	2	8	1.16		
Rise Time (20 to 80%)	t <sub>g+2-</sub>	2	-	-	1.0	3.0	4.5	-	-	ns	-	-	9	2	8	1.16		
Fall Time (20 to 80%)	t <sub>g+3+</sub>	2,3	-	-	1.1	2.0	4.5	-	-	ns	-	-	9	2,3	8	1.16		
Set Input																		
Propagation Delay	t <sub>s+2+</sub>	2	-	-	1.0	3.0	5.0	-	-	ns	-	-	5	2	8	1.16		
Reset Input	t <sub>s+15+</sub>	15	-	-	1.0	3.0	5.0	-	-	ns	-	-	12	15	8	1.16		
Propagation Delay	t <sub>s+3-</sub>	3	-	-	1.0	3.0	5.0	-	-	ns	-	-	5	3	8	1.16		
Toggle Frequency	t <sub>s+14-</sub>	14	-	-	1.0	3.0	5.0	-	-	ns	-	-	12	14	8	1.16		
Hold Time	t <sub>h</sub>	7	-	-	1.0	-	-	-	-	ns	-	-	6,9	5	2	8	1.16	
Toggle Frequency	t <sub>Tog</sub>	2	-	-	125	140	-	-	-	mHz	-	-	9	2	9	1.16		

NOTES

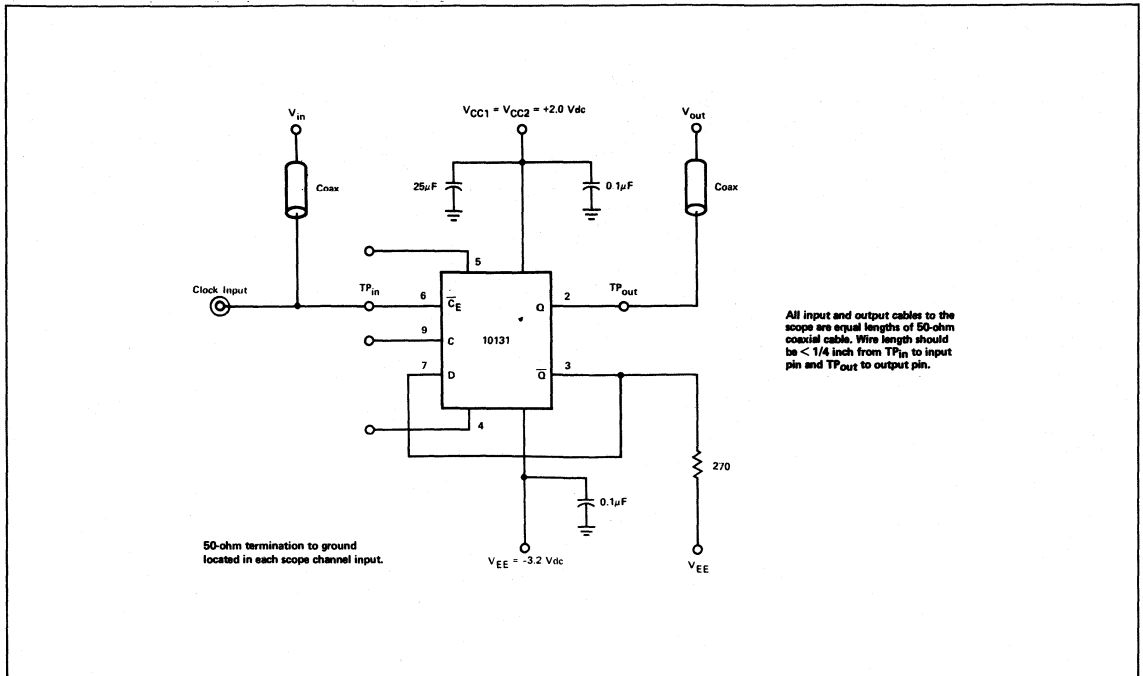
- ① Individually test each input; apply V<sub>IH</sub> max to pin under test.
- ② Individually test each input; apply V<sub>IL</sub> min to pin under test.
- ③ Output level to be measured after a clock pulse has been applied to the C input (pin 9)
- ④ Output level to be measured after a clock pulse has been applied to the C input (pin 9)
- ⑤ See Figure 2 for timing test diagram.



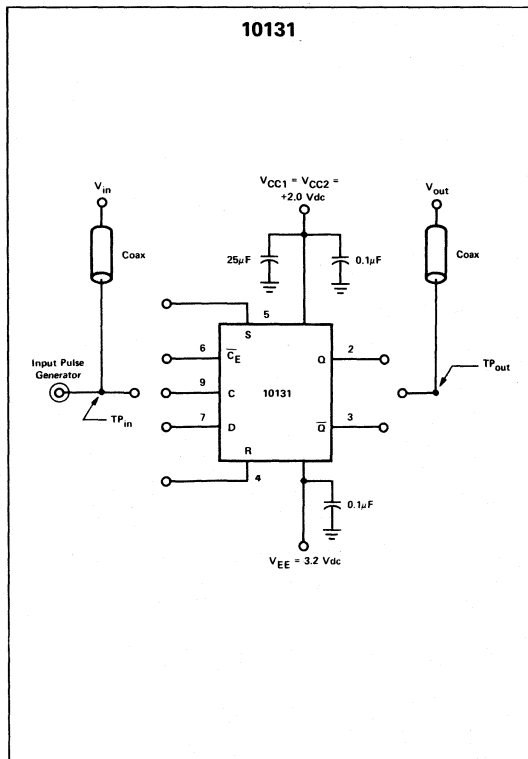
NOTES

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

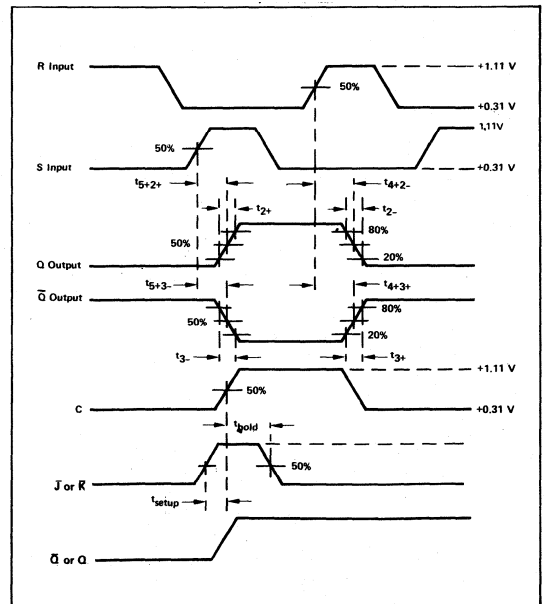
TOGGLE FREQUENCY TEST CIRCUIT



SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES

1.  $t_{setup}$  is the minimum time before the positive transition of the clock pulse (C) that information must be present at the inputs J or  $\bar{K}$ .
2.  $t_{hold}$  is the minimum time after the positive transition of the clock pulse (C) that information must remain unchanged at the inputs J or  $\bar{K}$ .

ADVANCE INFORMATION  
TO BE ANNOUNCED

10136F, 10137F: -30 to +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10136 and 10137 are high speed synchronous counters that can count up, count down, preset, or stop count at rates exceeding 100 MHz.

The 10136 is a 16-state (Hexadecimal) counter and the 10137 is a 10-state (Decade) counter.

The flexibility of these devices allows the designer to use one basic counter design for all applications. The synchronous count feature makes these MSI parts suitable for either computers or instrumentation.

The carry input enables the counter, and prevents it from changing state when the clock goes high. The inputs S1 and S2 control the state of the counter: stop count, increment (count up), decrement (count down), and preset (program) count. The other inputs are clock, and the four D inputs for presetting the counter.

The outputs include four Q's and a carry out which goes low on the terminal count. When an output is not needed, it can be left open to conserve system power.

The counter changes state only on the positive-going edge of the clock. Any other input may change at any time except during the positive transition of the clock. The next state of the counter is determined by the configuration of the inputs only during the positive transition of the clock.

### APPLICATIONS

Either the binary counter (10136) or the decade counter (10137) can be useful in high speed central processors and peripheral controllers, mini-computers, high speed digital communication equipment, and instrumentation.

When used as a prescaler, it is possible to extend the input frequency of the 10136, 37 to over 200 MHz with the 10231.

### FUNCTION SELECT TABLE

S1	S2	OPERATING MODE
L	L	Preset (Program)
L	H	Increment (Count Up)
H	L	Decrement (Count Down)
H	H	Hold (Stop Count)

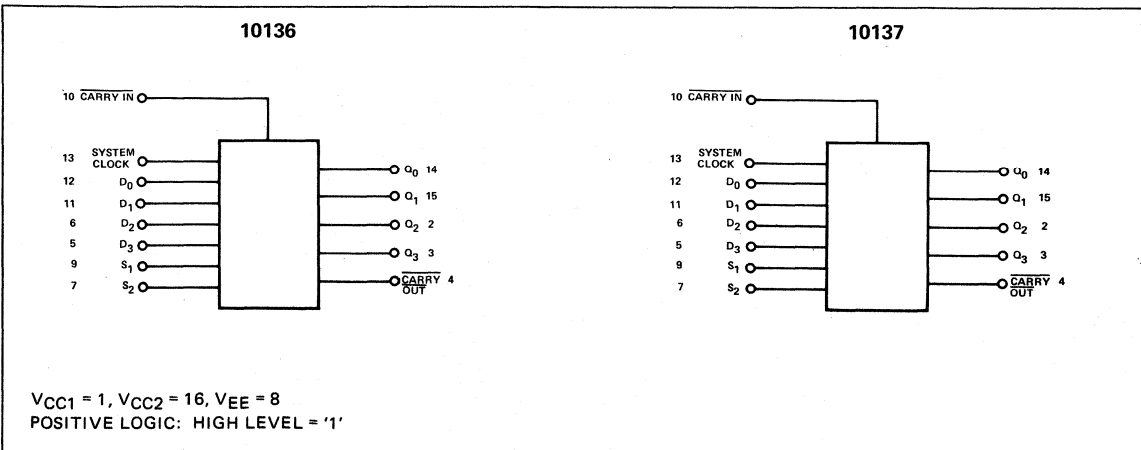
### TEMPERATURE RANGE

- 30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin CERDIP

### BLOCK DIAGRAMS



**Signetics**

**ECL HIGH PERFORMANCE  
256-PROM**

**10139**

**ADVANCED INFORMATION**

**DIGITAL 54/74 TTL SERIES**

**See Bipolar Memory Section page 4-33**

# Signetics

ECL 16x4 RAM | 10140  
10148  
10151

-30 to +85°C CERDIP

ADVANCED INFORMATION

DIGITAL 10,000 SERIES ECL

See Bipolar Memory Section page 4-37



10141F: -30 to +85°C

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10141 is a four-bit shift register that features four separate input terminals for parallel data entry and one each input terminal for serial shift left and serial shift right data entry. The device also provides an output terminal for each stage, thus allowing any combination of serial in/parallel in-serial out/parallel out operation modes to be used.

Two additional inputs are provided to control the four different operating modes of the device; parallel data entry, shift left, shift right, and stop. All shift operations occur on the positive-going edge of the clock input.

When operation of the device is restricted to one or two modes, the unused input/output pins can be left open since 50kΩ pull-down resistors are included on all input pins and all outputs are open-emitter. In addition, all outputs have 50Ω drive capability.

## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

## PACKAGE TYPE

F: 16 Pin CERDIP

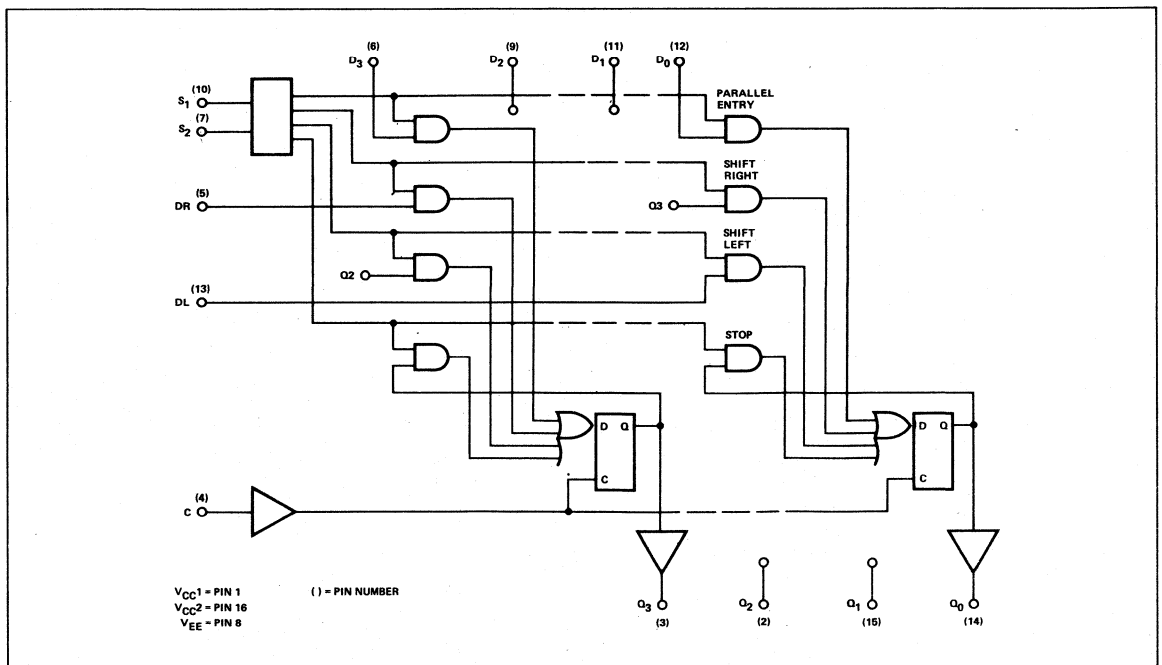
## FEATURES

- **HIGH SPEED**  
SHIFT FREQUENCY = 200 MHz (TYP)
- **LOW POWER**  
425 MW NO LOAD (TYP)
- **HIGH FANOUT - 50Ω DRIVE CAPABILITY**
- **HIGH Z INPUTS WITH 50kΩ PULLDOWN RESISTORS**
- **OPEN EMITTER OUTPUTS FOR BUSSING APPLICATIONS**
- **FOUR OPERATING MODES**
- **SERIAL AND PARALLEL DATA ENTRY**

## TRUTH TABLE

CONTROL		OPERATING MODE	OUTPUTS			
S <sub>1</sub>	S <sub>2</sub>		Q <sub>0(N+1)</sub>	Q <sub>1(H+1)</sub>	Q <sub>2(N+1)</sub>	Q <sub>3(N+1)</sub>
L	L	Parallel Entry	D <sub>0N</sub>	D <sub>1N</sub>	D <sub>2N</sub>	D <sub>3N</sub>
L	H	Shift Right	Q <sub>1N</sub>	Q <sub>2N</sub>	Q <sub>3N</sub>	D <sub>3N</sub>
H	L	Shift Left	D <sub>1N</sub>	Q <sub>0N</sub>	Q <sub>1N</sub>	Q <sub>2N</sub>
H	H	Stop Shift	Q <sub>0N</sub>	Q <sub>1N</sub>	Q <sub>2N</sub>	Q <sub>3N</sub>

## LOGIC DIAGRAM

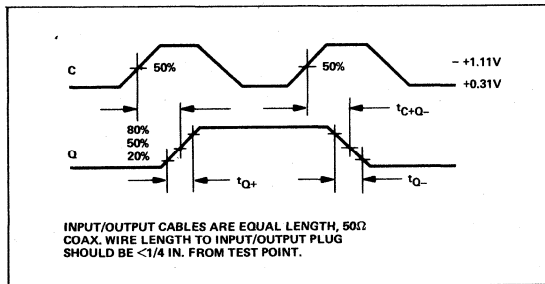
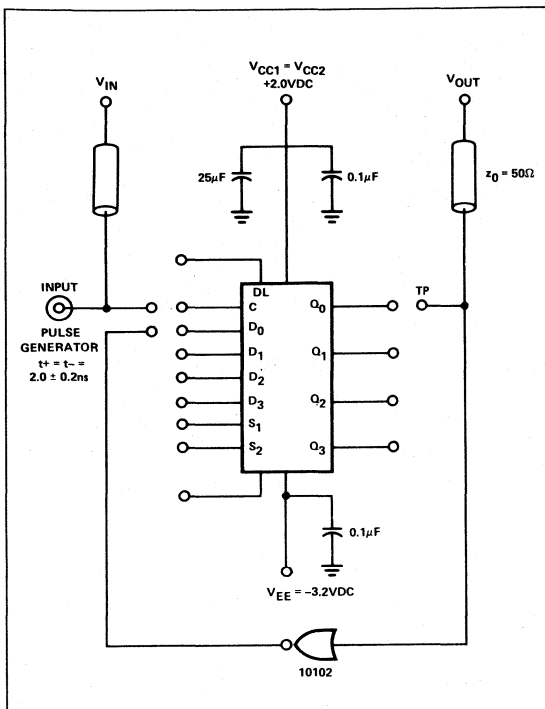




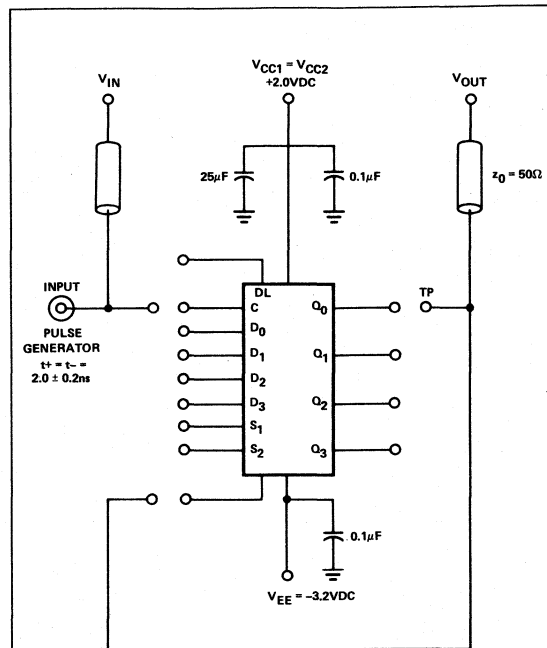
ELECTRICAL CHARACTERISTICS At Listed Voltages and Ambient Temperatures

																TEST VOLTAGE VALUES							
																(VOLTS)							
																V <sub>IH</sub> MAX	V <sub>IL</sub> MIN	V <sub>IHA</sub> MIN	V <sub>IILA</sub> MAX	V <sub>EE</sub>			
																@ Test Temperature							
																-30°C	-1.890	-1.890	-1.205	-1.500	-5.2		
																+25°C	-0.810	-1.850	-1.105	-1.475	-5.2		
																+85°C	-0.700	-1.825	-1.035	-1.440	-5.2		
																TEST VOLTAGE APPLIED TO PINS LISTED BELOW							
CHARACTERISTICS	SYMBOL	PIN UNDER TEST	TEST LIMITS						UNIT	TEST VOLTAGE APPLIED TO PINS LISTED BELOW					(V <sub>CC</sub> ) GND								
			-30°C		+25°C		+85°C			V <sub>IH</sub> MAX	V <sub>IL</sub> MIN	V <sub>IHA</sub> MIN	V <sub>IILA</sub> MAX	V <sub>EE</sub>									
Power Supply Drain Current	IE	8				82	102			mAdc					8	1,16							
Input Current	I <sub>INH</sub>	5					220			μAdc	5				8	1,16							
		6					220				6												
		7					245				7												
		4					265				4												
	I <sub>INL</sub>	12			0.5					μAdc	4,5,6,7,9,10,11,13	12			8	1,16							
Logic "1" Output Voltage	V <sub>OH</sub>	3	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	6,1				8	1,16							
Logic "0" Output Voltage	V <sub>OL</sub>	3	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	1				8	1,16							
Logic "1" Threshold Voltage 4	V <sub>OHA</sub>	3	-1.080		-0.980				-0.910	Vdc	1		6		8	1,16							
											6,1			7									
											6,2												
											3												
Logic "0" Threshold Voltage 5	V <sub>OLA</sub>	3		-1.655					-1.595	Vdc	1			6	8	1,16							
											1			7									
											2												
											6,3												
Switching Times (50Ω Load) 6																							
Propagation Delay	t <sub>4+3±</sub>	3	0.9	3.9	1.0	2.9	3.8	1.2	4.2	ns					8	1,16							
Setup Time (t <sub>setup</sub> )	t <sub>12±4±</sub>	14			2.5																		
Hold Time (t <sub>hold</sub> )	t <sub>4±12±</sub>	14			1.5																		
Rise Time (20% to 80%)	t <sub>3+</sub>	3	1.0	3.4	1.1	1.7	3.3	1.1	3.6														
Fall Time (20% to 80%)	t <sub>3-</sub>	3	1.0	3.4	1.1	1.7	3.3	1.1	3.6														
Shift Frequency	F <sub>SHIFT</sub>	-	150		150	200		150		MHz													
1	V <sub>IH</sub>	On pin 4																					
	V <sub>IL</sub>	On pin 4																					
2	V <sub>IHA</sub>	On pin 4																					
	V <sub>IL</sub>	On pin 4																					
3	V <sub>IILA</sub>	On pin 4																					
	V <sub>IL</sub>	On pin 4																					
4	Perform in sequence shown; reset to zero between each step.																						
5	Perform in sequence shown; reset to one between each step.																						
6	See switching time that circuit for procedures.																						

SWITCHING TIME TEST CIRCUIT



SHIFT FREQUENCY TEST CIRCUIT



TEST PROCEDURE

1. SET D<sub>1</sub>, D<sub>2</sub>, D<sub>3</sub> TO L (+0.31VDC)  
 SET D<sub>0</sub> TO H (+1.11VDC)
2. APPLY CLOCK PULSE  $\tau_L$  +1.11
3. MAINTAIN CLOCK LOW  
 SET S<sub>1</sub> TO L (+0.31VDC)  
 SET S<sub>2</sub> TO H (+1.11VDC)
4. MEASURE FREQUENCY

**Signetics**

**ECL 64x1 RAM 10145**

10145 F,1 -30°C to +85°C

**DIGITAL 10,000 ECL SERIES**

**See Bipolar Memory Section page 4-40**



10158F: -30 TO +85, CERDIP 10159F: -30 TO +85, CERDIP

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10158/10159 are high speed, low power quad 2-to-1 multiplexers which transmit data on either of two input pins to a common output pin in response to a single control signal. In addition, the 10159 features a common ENABLE input and inverting outputs, while the 10158 has non-inverting outputs and no enable.

Both devices feature high Z input pulldown resistors and open emitter outputs.

## FEATURES

- HIGH SPEED: PROPAGATION DELAY  
= 2.2 nS TYP DATA TO OUTPUT  
= 3.0 nS TYP SELECT TO OUTPUT
- OUTPUT ENABLE ON 10159 FOR OUTPUT BUSSING
- LOW POWER: 162 mW/PACKAGE TYP
- DRIVES 50Ω LINE
- STANDARD ECL 10,000 SERIES INTERFACE
- OPEN-EMITTER OUTPUTS

## APPLICATIONS

2-TO-1 MULTIPLEXER  
2-TO-1 DATA SELECTOR

## TEMPERATURE RANGE

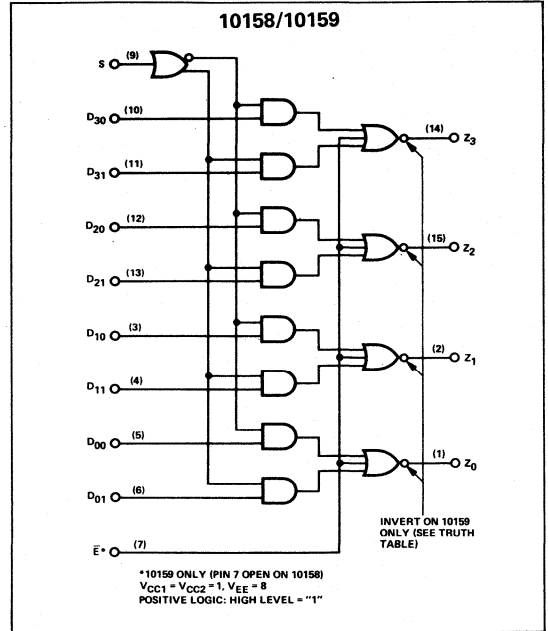
- -30 to +85 Operating Ambient

## PACKAGE TYPE

F: 16-Pin CERDIP

5-92

## LOGIC DIAGRAM



## TRUTH TABLE (10158)

INPUTS			OUTPUTS
Dno	Dni	S	Zn
L	X	L	L
H	X	L	H
X	L	H	L
X	H	H	H

X = Don't Care

## TRUTH TABLE (10159)

INPUTS				OUTPUTS
Dno	Dni	S	E	Zn
X	X	X	H	L
L	X	L	L	H
H	X	L	L	L
X	L	H	L	H
X	H	H	L	L

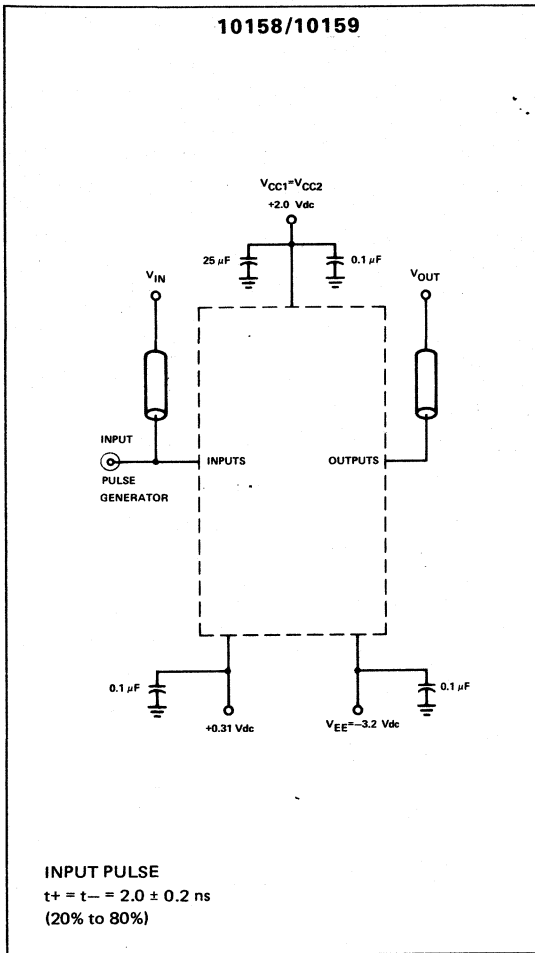
X = Don't Care

**ELECTRICAL CHARACTERISTICS**

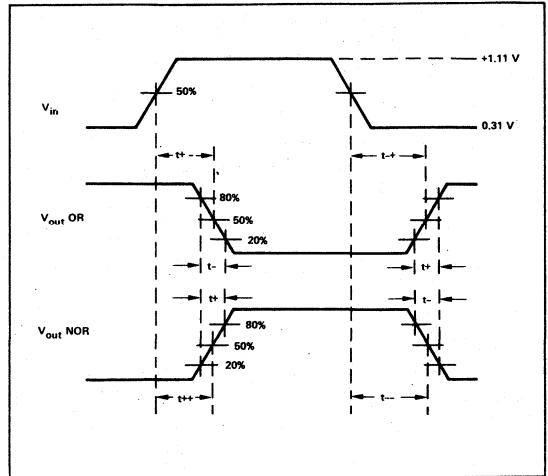
(at Listed Voltages and Ambient Temperatures).

Characteristics	Symbol	Pin Under Test	Test Limits								Unit	Test Voltage Values (Volts)					(Vcc) Gnd	
			-30°C		+25°C		+85°C		V <sub>IH</sub> Max	V <sub>IL</sub> Min		V <sub>IHA</sub> Min	V <sub>IILA</sub> Max	V <sub>EE</sub>				
			Min	Max	Min	Typ	Max	Min							Max			
			Test Voltage Applied to Pins Listed Below															
Power Supply Drain Current	I <sub>E</sub>	8				32					mAdc					8	16	
Input Current	I <sub>inH</sub>	4						265			mAdc	3				8	16	
	I <sub>inH</sub>	9						265			mAdc	9				8	16	
	I <sub>inH</sub>	7						575			mAdc	7				8	16	
	I <sub>inL</sub>	4				0.5					mAdc		3			8	16	
Logic "1" Output (10158)	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700		Vdc	3		9		8	16	
Voltage (10159)	V <sub>OH</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700		Vdc		3, 7, 9			8	16	
Logic "0" Output (10158)	V <sub>OL</sub>	2	-1.890	-1.075	-1.850	-	-1.650	-1.825	-1.615		Vdc			3, 9		8	16	
Voltage (10159)	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615		Vdc	3		7, 9		8	16	
Logic "1" Threshold	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-		Vdc			9	3	8	16	
Voltage (10159)	V <sub>OHA</sub>	2	-1.080	-	-0.980	-	-	-0.910	-		Vdc			3, 9		7	8	16
Logic "0" Threshold (10158)	V <sub>OLA</sub>	2	-	-1.655	-	-	-1.630	-	-1.595		Vdc			9		3	8	16
Voltage (10159)	V <sub>OLA</sub>	2	-	-1.655	-	-	-1.630	-	-1.595		Vdc	3		9		7	8	16
Switching Times												+1.11		Pulse IN	Pulse OUT	-3.2	+2.0	
Propagation Delay (10158)																		
(10159)	t <sub>3+2+</sub>	2			1.2	2.2	3.3			ns				3	2	8	16	
	t <sub>3-2-</sub>	2			1.2	2.2	3.3			ns				3	2	8	16	
	t <sub>9+2+</sub>	2			1.5	3.0	4.5			ns	4			9	2	8	16	
	t <sub>9-2-</sub>	2			1.5	3.0	4.5			ns	4			9	2	8	16	
	t <sub>3+2-</sub>	2			1.2	2.2	3.3			ns				3	2	8	16	
	t <sub>3-2+</sub>	2			1.2	2.2	3.3			ns				3	2	8	16	
	t <sub>9+2+</sub>	2			1.5	3.0	4.5			ns	3			9	2	8	16	
	t <sub>9-2-</sub>	2			1.5	3.0	4.5			ns	3			9	2	8	16	
	t <sub>7+2-</sub>	2			1.5	3.0	4.5			ns				7	2	8	16	
	t <sub>7-2+</sub>	2			1.5	3.0	4.5			ns				7	2	8	16	
Rise Time (20% to 80%)	t <sub>+</sub>				2.0					ns				3	2	8	16	
Fall Time (20% to 80%)	t <sub>-</sub>				2.0					ns				3	2	8	16	

SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES:

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be <1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
5. One input from each gate must be tied to V<sub>BB</sub> (Pin 11) during testing.

10160F: -30 to +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10160 is a high performance parity circuit constructed with nine EXCLUSIVE-OR gates in a single package, internally connected to provide odd parity checking or generation.

Input pulldown resistors ensure that the unconnected inputs are pulled to low logic level allowing parity detection and generation for less than 12 bits.

The Output goes high with ODD parity on input pins 3 through 15. (That is, if there are 1,3,5,7,9 or 11 '1's on these inputs.)

Expansion for word lengths greater than 12 bits can be achieved by connecting to the carry inputs of the 10170 Parity Circuit or by using 10107 or 10113 EXCLUSIVE-OR gates.

## FEATURES

- HIGH FUNCTIONAL DENSITY ON ONE CHIP REDUCES PACKAGE COUNT AND SAVES SYSTEM POWER
- FAST PROPAGATION DELAY = 4.0ns TYP
- LOW POWER DISSIPATION = 325mW/PACKAGE TYPE (NO LOAD)
- HIGH FANOUT CAPABILITY. — CAN DRIVE 50Ω LINES
- HIGH Z INPUTS — INTERNAL 50kΩ PULLDOWNS
- CONTROLLED OUTPUT RISE AND FALL TIMES -2.0ns TYP (20% TO 80%) (OUTPUT LOADED)
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2V \pm 5\%$  RECOMMENDED
- OPEN EMITTER LOGIC AND BUSSING CAPABILITY

## APPLICATIONS

### DETECTION OR GENERATION OF PARITY IN:

High Speed Central Processors  
High Speed Peripherals  
High Speed Minicomputers  
Communication Systems  
Instrumentation

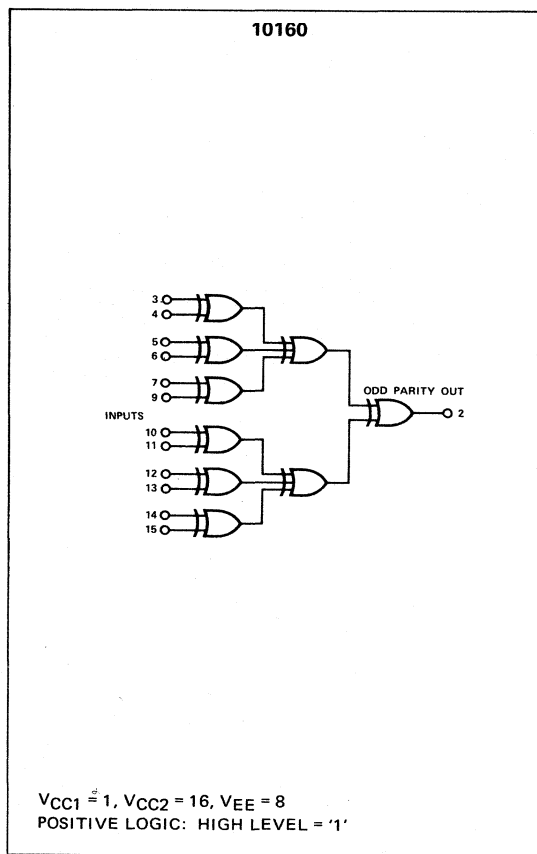
## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

## PACKAGE TYPE

F: 16-Pin CERDIP

## LOGIC DIAGRAM



## TRUTH TABLE

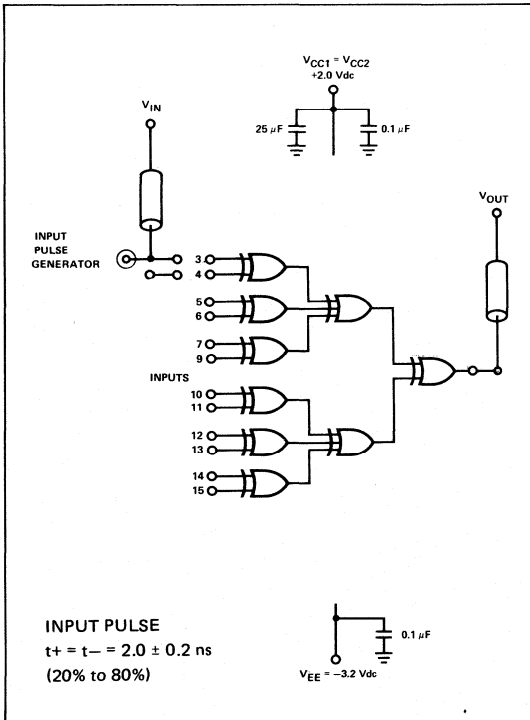
INPUT	OUTPUT
Sum of High Level Inputs	Pin 2
Even	Low
Odd	High

ELECTRICAL CHARACTERISTICS

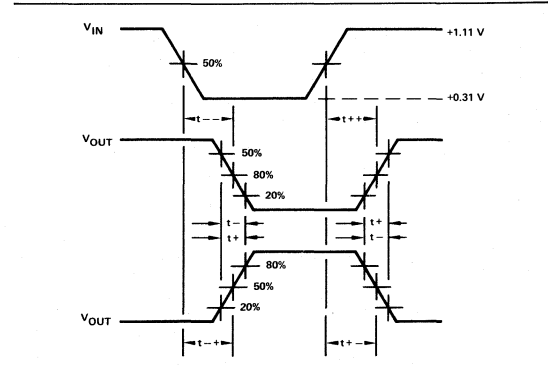
(at Listed Voltages and Ambient Temperatures).

Characteristic	Symbol	Pin Under Test	10160 Test Limits						Unit	TEST VOLTAGE VALUES					(V <sub>CC</sub> ) Gnd	
			-30°C		+25°C		+85°C			(Volts)						
			Min	Max	Min	Typ	Max	Min		Max	V <sub>IHmax</sub>	V <sub>ILmin</sub>	V <sub>IHAmin</sub>	V <sub>ILAmx</sub>		V <sub>EE</sub>
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	62	78	-	-	mAdc	4,5,9,10,13,14	-	-	-	8	1.16
Input Current	I <sub>inH</sub>	3	-	-	-	-	265	-	-	μAdc	3	-	-	-	8	1.16
	I <sub>inL</sub>	4	-	-	-	-	265	-	-	μAdc	4	-	-	-	8	1.16
Logic "1" Output Voltage	V <sub>OH</sub>	3	-	-	0.5	-	-	-	-	μAdc	-	3	-	-	8	1.16
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	3	4,5,6,7,9,10,11,12,13,14,15	-	-	8	1.16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	3,4,5,6,7,9,10,11,12,13,14,15	-	-	8	1.16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	-	-1.080	-	-	-	-0.910	-	Vdc	-	4,5,6,7,9,10,11,12,13,14,15	3	-	8	1.16
Switching Times (50Ω Load)																
Propagation Delay											+1.11 V		Pulse in	Pulse out	-3.2 V	+2.0 V
	t <sub>3+2+</sub>	2	-	-	-	4.0	-	-	-	ns	-	-	3	2	8	1.16
	t <sub>3+2-</sub>	2	-	-	-	4.0	-	-	-	ns	4	-	3	2	8	1.16
	t <sub>3-2+</sub>	2	-	-	-	4.0	-	-	-	ns	-	-	3	2	8	1.16
	t <sub>3-2-</sub>	2	-	-	-	4.0	-	-	-	ns	4	-	3	2	8	1.16
	t <sub>4+2+</sub>	2	-	-	-	4.0	-	-	-	ns	-	-	4	2	8	1.16
	t <sub>4+2-</sub>	2	-	-	-	4.0	-	-	-	ns	3	-	4	2	8	1.16
	t <sub>4-2+</sub>	2	-	-	-	4.0	-	-	-	ns	-	-	4	2	8	1.16
	t <sub>4-2-</sub>	2	-	-	-	4.0	-	-	-	ns	3	-	4	2	8	1.16
Rise Time (20% to 80%)	t <sub>2+</sub>	2	-	-	-	2.0	-	-	-	ns	-	-	3	2	8	1.16
Fall Time (20% to 80%)	t <sub>2-</sub>	2	-	-	-	2.0	-	-	-	ns	-	-	3	2	8	1.16

SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope channel input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.



10161F: -30 to +85°C, CERDIP

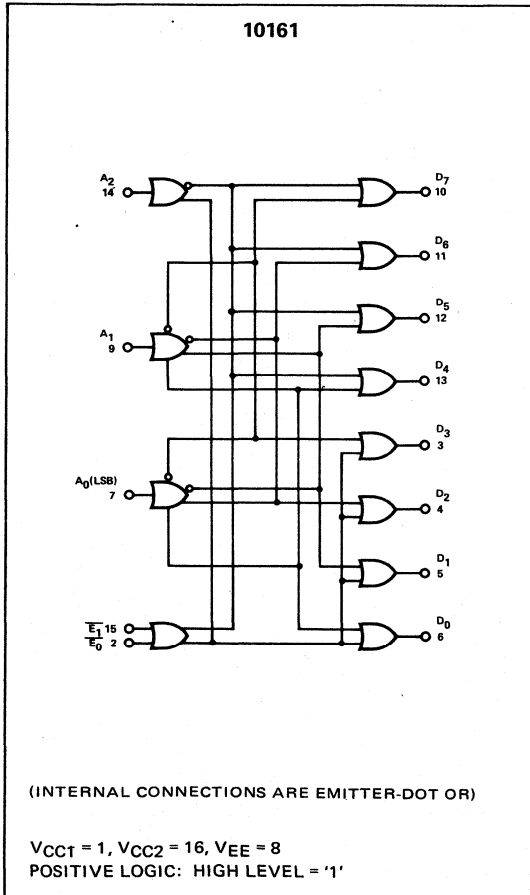
DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10161 is a binary coded 3 line to 8 line decoder. Outputs are normally high with the selected output going low. Two enable inputs make it ideally suited for demultiplexer applications. One of the two enable inputs can be used as the data enable input. Either enable input when high, forces all outputs high.

The 10161 is a true parallel decoder using internal emitter dotting techniques. Hence it eliminates unequal delay times found in other decoders. The 10161 is a low power, high speed device with high Z input pulldown resistors and open emitter outputs.

## LOGIC DIAGRAM



## FEATURES

- FAST PROPAGATION DELAY  
 = 4.0 ns TYP ADDRESS TO OUTPUT  
 = 4.5 ns TYP ENABLE TO OUTPUT
- LOW POWER DISSIPATION = 295 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE EIGHT 50 Ω LINES
- TRUE PARALLEL DECODER – ELIMINATES UNEQUAL DELAY TIMES
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- OPEN EMITTER OUTPUTS
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

## APPLICATIONS

- 1 of 8 Decoder
- 1 line to 8 line Demultiplexer

## TRUTH TABLE

ENABLE INPUTS		INPUTS			OUTPUTS							
E1	E0	A2	A1	A0	D0	D1	D2	D3	D4	D5	D6	D7
L	L	L	L	L	L	H	H	H	H	H	H	H
L	L	L	L	H	L	H	L	H	H	H	H	H
L	L	L	L	H	H	H	L	H	H	H	H	H
L	L	L	H	L	L	H	H	L	H	H	H	H
L	L	L	H	L	H	H	H	L	H	H	H	H
L	L	L	H	H	L	H	H	H	L	H	H	H
L	L	H	L	L	H	H	H	H	H	L	H	H
L	L	H	L	H	L	H	H	H	H	H	L	H
L	L	H	H	L	H	H	H	H	H	H	L	H
L	L	H	H	H	L	H	H	H	H	H	L	H
H	L	φ	φ	φ	H	H	H	H	H	H	H	H
L	H	φ	φ	φ	H	H	H	H	H	H	H	H
H	H	φ	φ	φ	H	H	H	H	H	H	H	H

φ = Don't Care.

## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- F: 16-Pin CERDIP

**ELECTRICAL CHARACTERISTICS**  
(at Listed Voltages and Ambient Temperatures).

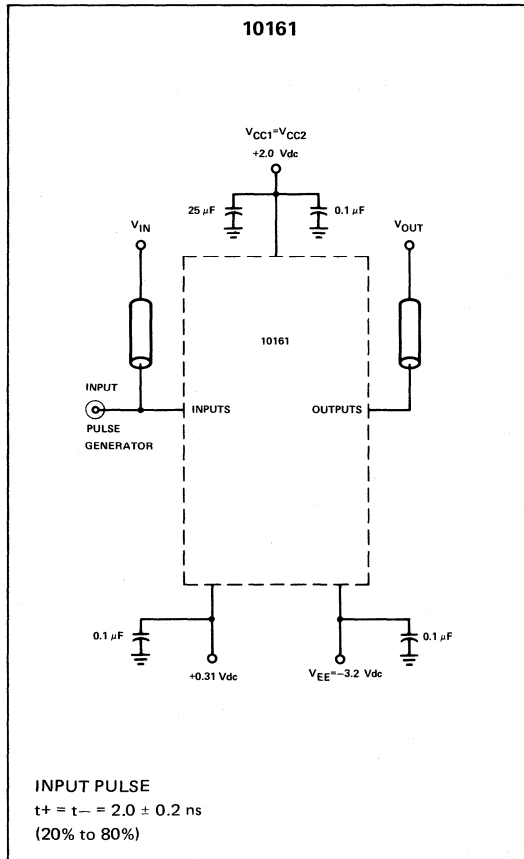
		TEST VOLTAGE VALUES (Volts)						
		Temperature						
		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>I LA</sub> max	V <sub>EE</sub>		
-30° C		-0.890	-1.890	-1.205	-1.500	-5.2		
+25° C		-0.810	-1.850	-1.105	-1.475	-5.2		
+85° C		-0.700	-1.825	-1.035	-1.440	-5.2		

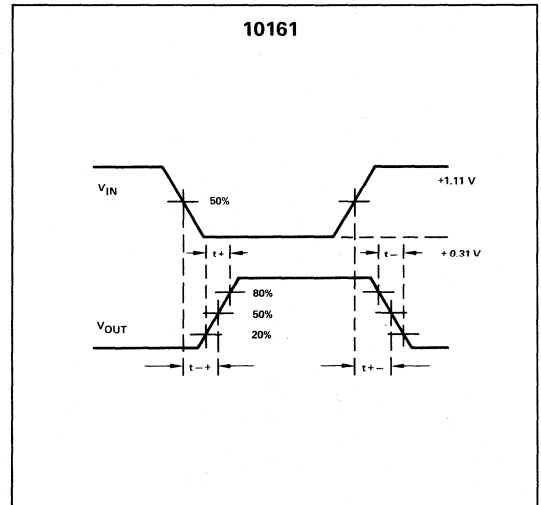
		TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(V <sub>CC</sub> )
		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>I LA</sub> max	V <sub>EE</sub>	Gnd
Power Supply Drain Current	I <sub>E</sub>	2,7,9,14,15	—	—	—	8	1,16
Input Current	I <sub>inH</sub>	14	—	—	—	8	1,16
	I <sub>inL</sub>	14	—	—	—	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	13	—	—	—	8	1,16
	V <sub>OL</sub>	13	—	—	—	8	1,16
Logic "0" Output Voltage	V <sub>OH</sub>	13	—	—	—	8	1,16
	V <sub>OL</sub>	13	—	—	—	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	13	—	—	—	8	1,16
	V <sub>OLA</sub>	13	—	—	—	8	1,16
Logic "0" Threshold Voltage	V <sub>OHA</sub>	13	—	—	—	8	1,16
	V <sub>OLA</sub>	13	—	—	—	8	1,16
Switching Times * (50-ohm load)	Propagation Delay	t <sub>14+ 13-</sub>	13	—	—	4.0	—
	Rise Time (20% to 80%)	t <sub>13+</sub>	13	—	—	2.0	—
Fall Time (20% to 80%)	t <sub>13-</sub>	13	—	—	2.0	—	—

\*Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 6 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10162F: -30 to +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

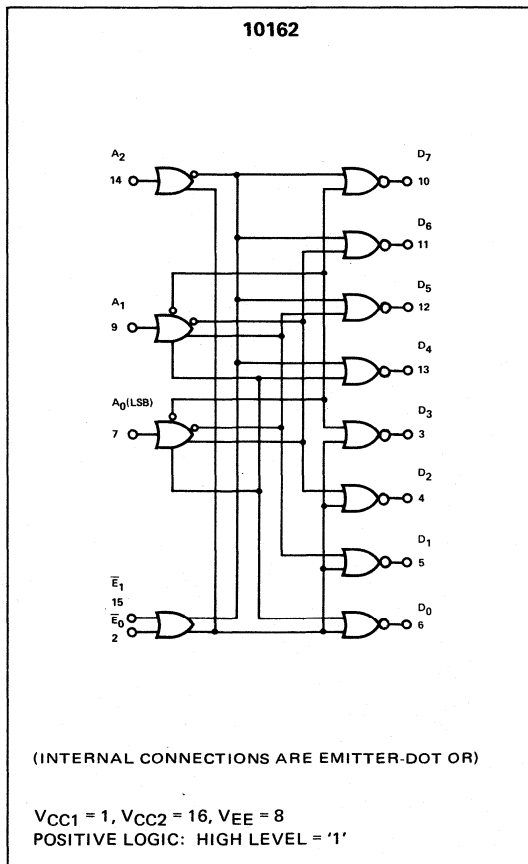
The 10162 is a binary coded 3 line to 8 line decoder. Outputs are normally low with the selected output going high. Two enable inputs make it ideally suited for demultiplexer applications. One of the two enable inputs can be used as the data enable input. Either enable input when high, forces all outputs low.

The 10162 is a true parallel decoder using internal emitter dotting techniques. Hence it eliminates unequal delay times found in other decoders. The 10162 is a low power, high speed device with high Z input pulldown resistors and open emitter outputs.

### FEATURES

- FAST PROPAGATION DELAY  
= 4.0 ns TYP ADDRESS TO OUTPUT  
= 4.5 ns TYP ENABLE TO OUTPUT
- LOW POWER DISSIPATION = 295 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY - CAN DRIVE EIGHT 50 Ω LINES
- TRUE PARALLEL DECODER - ELIMINATES UNEQUAL DELAY TIMES
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- OPEN EMITTER OUTPUTS
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

### LOGIC DIAGRAM



### APPLICATIONS

- 1 of 8 Decoder
- 1 line to 8 line Demultiplexer

### TRUTH TABLE

INPUTS					OUTPUTS							
E1	E0	A2	A1	A0	D0	D1	D2	D3	D4	D5	D6	D7
L	L	L	L	L	H	L	L	L	L	L	L	L
L	L	L	L	H	L	H	L	L	L	L	L	L
L	L	L	H	L	L	L	H	L	L	L	L	L
L	L	L	H	H	L	L	L	H	L	L	L	L
L	L	H	L	L	L	L	L	L	H	L	L	L
L	L	H	L	H	L	L	L	L	L	H	L	L
L	L	H	H	L	L	L	L	L	L	L	H	L
L	L	H	H	H	L	L	L	L	L	L	L	H
H	L	φ	φ	φ	L	L	L	L	L	L	L	L
L	H	φ	φ	φ	L	L	L	L	L	L	L	L
H	H	φ	φ	φ	L	L	L	L	L	L	L	L

φ = Don't Care.

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin CERDIP

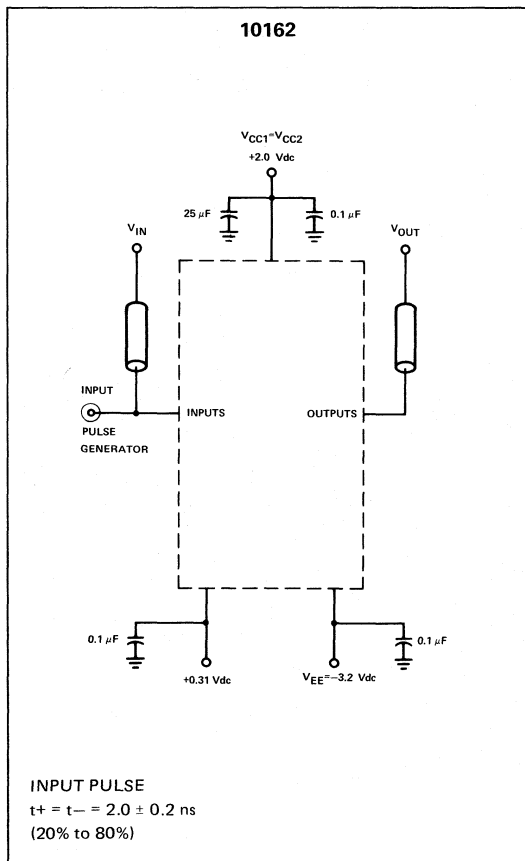
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

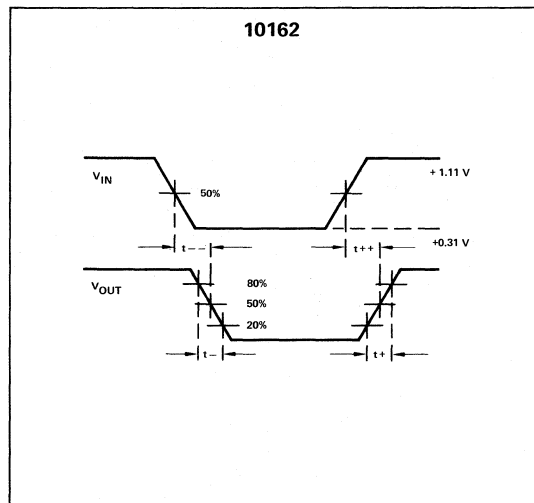
Characteristic	Symbol	Pin Under Test	10162 Test Limits								Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(V <sub>CC</sub> ) Gnd	
			-30° C		+25° C			+85° C				V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>		
			Min	Max	Min	Typ	Max	Min	Max	Min		Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max		V <sub>EE</sub>
			-30° C		+25° C			+85° C				TEST VOLTAGE VALUES						
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	57	72	—	—	mAdc	—	—	—	—	8	1,16		
Input Current	I <sub>inH</sub>	14	—	—	—	—	265	—	—	μAdc	14	—	—	—	8	1,16		
	I <sub>inL</sub>	14	—	—	0.5	—	—	—	—	μAdc	—	14	—	—	8	1,16		
Logic "1" Output Voltage	V <sub>OH</sub>	13	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	14	—	—	—	8	1,16		
Logic "0" Output Voltage	V <sub>OL</sub>	13	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	2	—	—	—	8	1,16		
Output Voltage		13	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	15	—	—	—	8	1,16		
Logic "1" Threshold Voltage	V <sub>OHA</sub>	13	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	14	—	8	1,16		
Logic "0" Threshold Voltage	V <sub>OLA</sub>	13	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	2	—	8	1,16		
Switching Times * (50-ohm load)													Pulse In	Pulse Out	-3.2 V	+2.0 V		
Propagation Delay	t <sub>14+ 13+</sub>	13	—	—	—	4.0	—	—	—	ns	—	—	14	13	8	1,16		
Rise Time (20% to 80%)	t <sub>+</sub>	13	—	—	—	4.0	—	—	—	↓	—	—	↓	↓	↓	↓		
Fall Time (20% to 80%)	t <sub>-</sub>	13	—	—	—	2.0	—	—	—	↓	—	—	↓	↓	↓	↓		

\*Unused outputs connected to 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25° C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10164F: -30 to +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

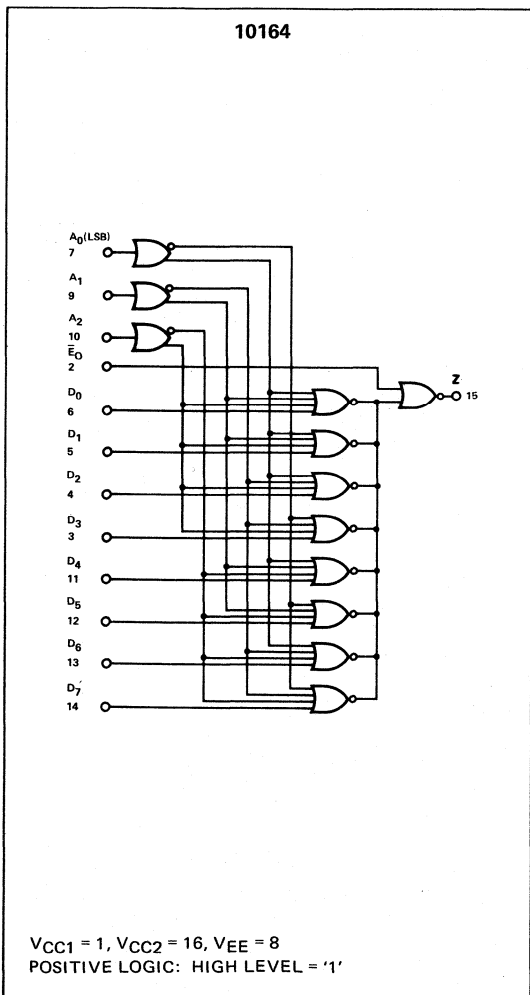
## DESCRIPTION

The 10164 is a high speed, low power 8 to 1 multiplexer/data selector which routes data present at one-of-eight inputs to the output. The data is routed according to the three bit code present on the address inputs. An enable input is provided for easy bit expansion. The 10164 has high Z input pulldown resistors and open emitter outputs.

## FEATURES

- FAST PROPAGATION DELAY  
= 3.5 ns TYP DATA TO OUTPUT  
= 5.0 ns TYP ADDRESS TO OUTPUT  
= 2.0 ns TYP ENABLE TO OUTPUT
- OUTPUT ENABLE TO PERMIT OUTPUT BUSSING
- LOW POWER DISSIPATION = 290 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE A 50 Ω LINE
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

## LOGIC DIAGRAM



## APPLICATIONS

- 8 to 1 Multiplexer
- 8 to 1 Data Selector
- Parallel to Serial Conversion
- Barrel Shift Logic

## TRUTH TABLE

ENABLE	ADDRESS INPUTS			Z
	A2	A1	A0	
L	L	L	L	D0
L	L	L	H	D1
L	L	H	L	D2
L	L	H	H	D3
L	H	L	L	D4
L	H	L	H	D5
L	H	H	L	D6
L	H	H	H	D7
H	φ	φ	φ	L

φ = Don't Care.

## TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

## PACKAGE TYPE

- F: 16-Pin CERDIP

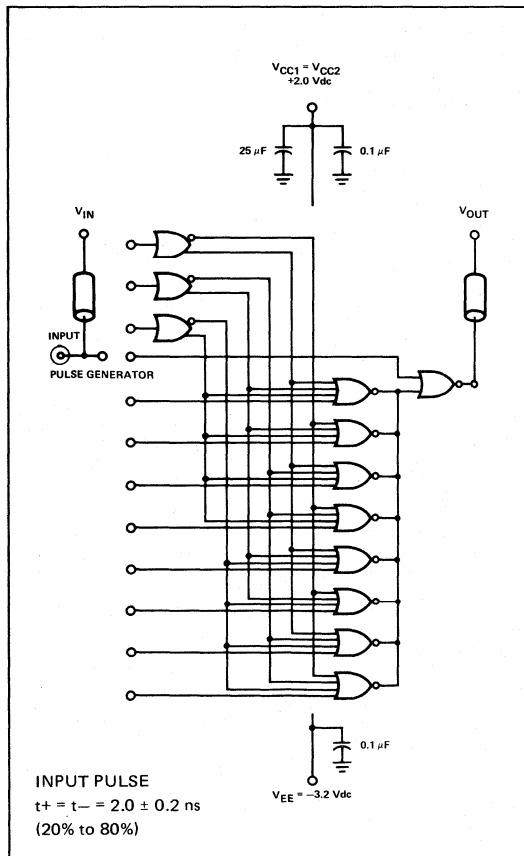
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

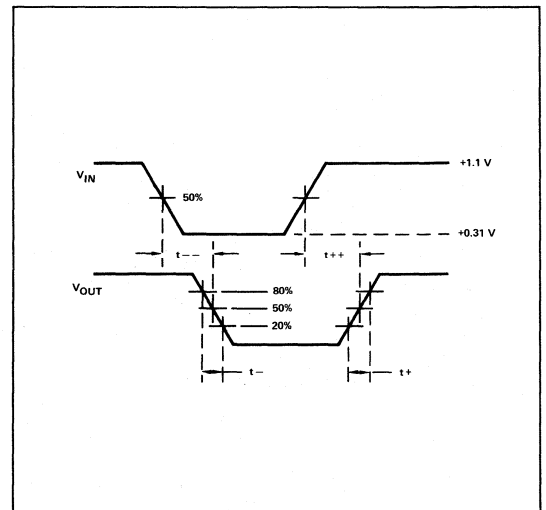
@ Test Temperature	TEST VOLTAGE VALUES (Volts)				
	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VLA</sub> max	V <sub>EE</sub>
-30°C	-0.890	-1.890	-1.205	-1.500	-5.2
+25°C	-0.810	-1.850	-1.105	-1.475	-5.2
+85°C	-0.700	-1.825	-1.035	-1.440	-5.2

Characteristic	Symbol	Pin Under Test	10164 Test Limits								Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(V <sub>CC</sub> ) Gnd
			-30°C		+25°C			+85°C				V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VLA</sub> max	V <sub>EE</sub>	
			Min	Max	Min	Typ	Max	Min	Max	Min		Max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VLA</sub> max	V <sub>EE</sub>	
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	56	75	-	-	mAdc	-	-	-	-	8	1,16	
Input Current	i <sub>INH</sub>	4	-	-	-	-	220	-	-	μAdc	4	-	-	-	8	1,16	
	i <sub>INL</sub>	4	-	-	0.5	-	-	-	-	μAdc	-	4	-	-	8	1,16	
Logic "1" Output Voltage	V <sub>O1H</sub>	15	-1.090	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	4,9	-	-	-	8	1,16	
Logic "0" Output Voltage	V <sub>O1L</sub>	15	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	9	-	-	-	8	1,16	
Logic "1" Threshold Voltage	V <sub>O1HA</sub>	15	-1.090	-	-0.980	-	-	-	-0.910	Vdc	4,9	-	-	2	8	1,16	
Logic "0" Threshold Voltage	V <sub>O1LA</sub>	15	-	-1.655	-	-	-1.630	-	-1.595	Vdc	9	-	-	2	8	1,16	
Switching Times* (50 Ωload)											+1.11 V		Pulse In	Pulse Out	-8.2 V	+2.0 V	
Propagation Delay	14+ 15+	15	-	-	-	3.5	-	-	-	ns	9	-	4	15	8	1,16	
	14- 15-	15	-	-	-	3.5	-	-	-	ns	9	-	4				
	17+ 15+	15	-	-	-	5.0	-	-	-	ns	5	-	7				
	17- 15-	15	-	-	-	5.0	-	-	-	ns	5	-	7				
	12+ 15+	15	-	-	-	2.0	-	-	-	ns	7,5	-	2				
	12- 15+	15	-	-	-	2.0	-	-	-	ns	7,5	-	2				
Rise Time (20% to 80%)	t <sub>r</sub>	15	-	-	-	2.0	-	-	-	ns	9	-	4				
Fall Time (20% to 80%)	t <sub>f</sub>	15	-	-	-	2.0	-	-	-	ns	9	-	4				

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope channel input.
- Test procedures are shown for only one input or for one set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10170F: -30 TO +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10170 is a high performance parity circuit constructed with triple EXCLUSIVE-OR gates. The function is optimized for use in byte organized systems. The device can generate or check 9 bits of parity in 2 gates delays. Larger word lengths to 27 bits can be checked in 3 gate delays by connecting output A of other 10170's to the carry inputs. The carry inputs may also be used for ODD/EVEN parity control.

Output A goes high with ODD parity on input pins 3 through 12. (That is, if there are 1,3,5,7, or 9 '1's on these inputs.) Output B goes high for ODD parity on output A and carry input pins 13 and 14. (That is, if there are 1,3,5,7,9 or 11 '1's on input pins 3 through 14.)

### FEATURES

- OPTIMIZED FOR BYTE-ORGANIZED SYSTEMS
- FAST PROPAGATION DELAY
  - = 4.0ns TYP (INPUT TO OUTPUT A)
  - = 6.0ns TYP (INPUT TO OUTPUT B)
  - = 2.0ns TYP (CARRY TO OUTPUT B)
- CARRY INPUTS FOR EASY EXPANSION OR ODD/EVEN CONTROL
- UP TO 9 BIT CHECK IN 4.0ns
- UP TO 27 BIT CHECK IN 6.0ns WITH NO ADDITIONAL GATES REQUIRED
- LOW POWER DISSIPATION = 280mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY — CAN DRIVE 50Ω LINES
- HIGH Z INPUTS — INTERNAL 50kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS
- OPEN EMITTER OUTPUTS FOR LOGIC AND BUS-SING CAPABILITY

### APPLICATIONS

#### DETECTION OR GENERATION OF PARITY IN:

High Speed Central Processors  
High Speed Peripherals  
High Speed Minicomputers  
Communication Systems  
Instrumentation

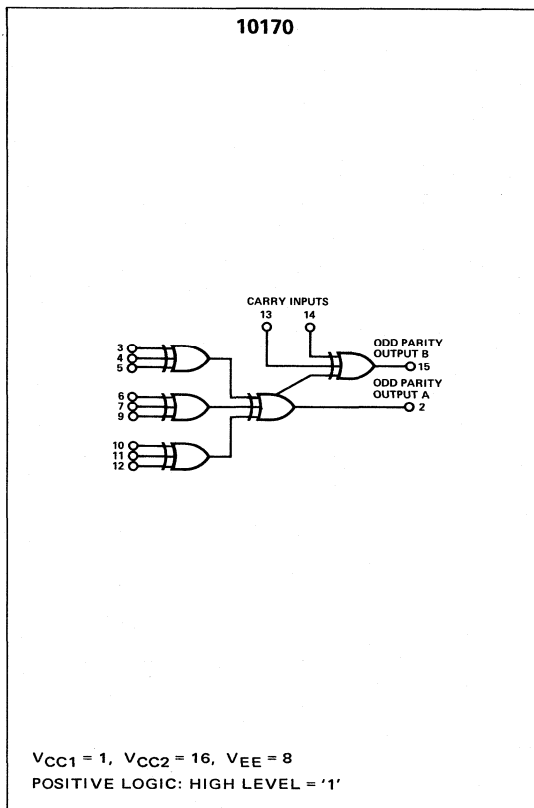
### TEMPERATURE RANGE

-30 to +85°C Operating Ambient

### PACKAGE TYPE

F: 16-Pin CERDIP

### LOGIC DIAGRAM



### TRUTH TABLE

INPUT	OUTPUT
SUM OF HIGH LEVEL INPUTS PINS 3-12	PIN 2
EVEN	LOW
ODD	HIGH
SUM OF ALL HIGH LEVEL INPUTS (INCLUDING CARRY INPUTS)	PIN 15
EVEN	LOW
ODD	HIGH

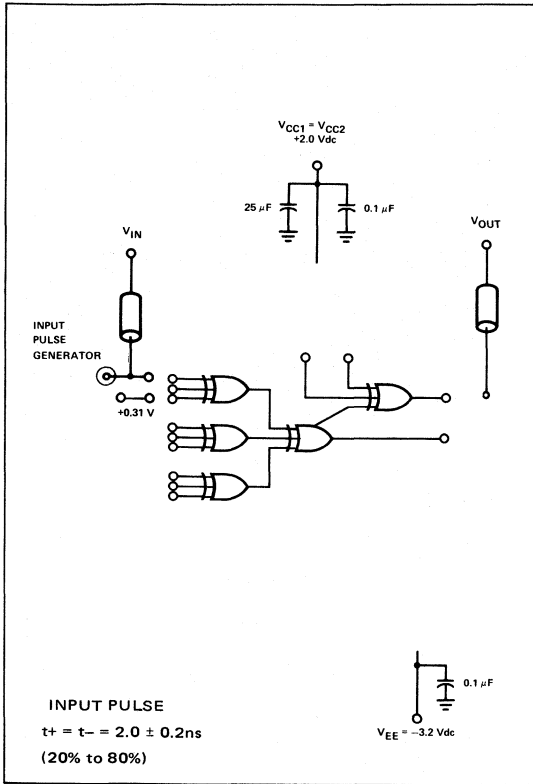
# SIGNETICS 9-BIT PARITY CIRCUIT (WITH 2 CARRY INPUTS) ■ 10170

## ELECTRICAL CHARACTERISTICS (at Listed Voltages and Ambient Temperatures).

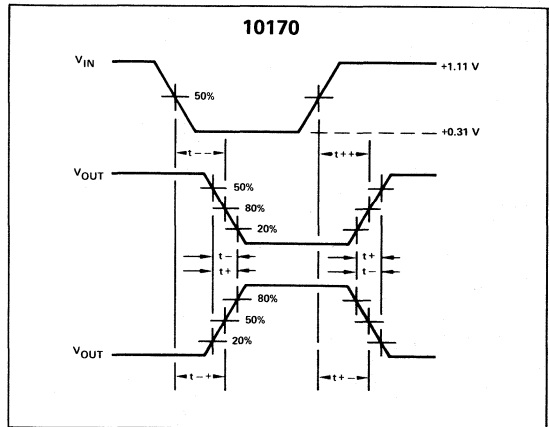
Characteristic	Symbol	Pin Under Test	10170 Test Limits						Unit	TEST VOLTAGE VALUES (Volts)					(Vcc) Gnd	
			-30°C		+25°C		+85°C			VIHmax	VI Lmin	VIHamin	VI LAmax	VEE		
			Min	Max	Min	Typ	Max	Min		Max	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					
Power Supply Drain Current	IE	8	-	-	-	54	68	-	-	mAdc	4,5,9,10,13,14	-	-	-	8	1.16
Input Current	IinH	3	-	-	-	-	265	-	-	μAdc	3	-	-	-	8	1.16
	IinL	14	-	-	-	-	265	-	-	μAdc	14	-	-	-	8	1.16
Logic "1" Output Voltage	VOH	3	-	-	0.5	-	-	-	-	μAdc	-	3	-	-	8	1.16
		14	-	-	0.5	-	-	-	-	μAdc	-	14	-	-	8	1.16
Logic "0" Output Voltage	VOL	2	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	3	4,5,6,7,9,10 11,12,13,14	-	-	8	1.16
		15	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	3	4,5,6,7,9,10 11,12,13,14	-	-	8	1.16
Logic "1" Threshold Voltage	VOHA	2	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	3,4,5,6,7,9,10 11,12,13,14	-	-	8	1.16
		15	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	3,4,5,6,7,9,10 11,12,13,14	-	-	8	1.16
Logic "0" Threshold Voltage	VOLA	2	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	4,5,6,7,9,10 11,12,13,14	3	-	8	1.16
		15	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	4,5,6,7,9,10 11,12,13,14	3	-	8	1.16
Switching Times (50-ohm Load) Propagation Delay	t3+2+	2	-	-	2.0	4.0	6.0	-	-	ns	+1.11 V	-	Pulse in	Pulse out	-3.2V	+2.0V
		15	-	-	2.0	4.0	6.0	-	-	ns	-	-	3	2	8	1.16
Rise Time (20% to 80%) Fall Time (20% to 80%)	t3+2-	2	-	-	2.0	4.0	6.0	-	-	ns	-	-	3	2	8	1.16
	t3-2+	2	-	-	2.0	4.0	6.0	-	-	ns	-	-	3	2	8	1.16
	t3-2-	2	-	-	2.0	4.0	6.0	-	-	ns	-	-	3	2	8	1.16
	t3+15+	15	-	-	3.0	6.0	9.0	-	-	ns	-	-	3	15	8	1.16
	t3+15-	15	-	-	3.0	6.0	9.0	-	-	ns	-	-	3	15	8	1.16
	t3-15+	15	-	-	3.0	6.0	9.0	-	-	ns	-	-	3	15	8	1.16
	t3-15-	15	-	-	3.0	6.0	9.0	-	-	ns	-	-	3	15	8	1.16
	t13+15+	15	-	-	1.0	2.0	3.0	-	-	ns	-	-	13	15	8	1.16
	t13+15-	15	-	-	1.0	2.0	3.0	-	-	ns	-	-	13	15	8	1.16
	t13-15+	15	-	-	1.0	2.0	3.0	-	-	ns	-	-	13	15	8	1.16
	t13-15-	15	-	-	1.0	2.0	3.0	-	-	ns	-	-	13	15	8	1.16
	Rise Time (20% to 80%)	t2+	2	-	-	1.1	2.0	3.3	-	-	ns	-	-	3	2	8
Fall Time (20% to 80%)	t2-	2	-	-	1.1	2.0	3.3	-	-	ns	-	-	3	2	8	1.16
	t15+	15	-	-	1.1	2.0	3.3	-	-	ns	-	-	3	15	8	1.16
	t15-	15	-	-	1.1	2.0	3.3	-	-	ns	-	-	3	15	8	1.16



SWITCHING TIME TEST CIRCUIT



PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES

1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from  $TP_{in}$  to input pin and  $TP_{out}$  to output pin. A 50-ohm termination to ground is located in each scope channel input. Unused outputs are connected to a 50-ohm resistor to ground.
3. Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
4. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10171F: -30 to +85°C, CERDIP

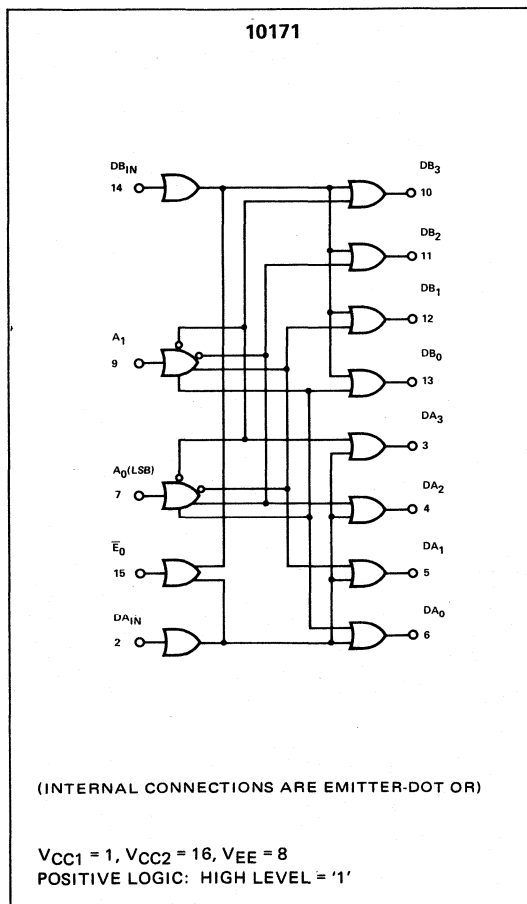
DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10171 is a binary coded 2 line to dual 4 line decoder/demultiplexer. Outputs are normally high with the selected outputs going low. There are two parallel 1 line to 4 line non-inverting data paths and a common enable input. Each data input when high forces its four outputs high. The enable input when high forces all eight outputs high.

The 10171 is a true parallel decoder using internal emitter dotting techniques. Hence it eliminates unequal delay times found in other decoders. The 10171 is a low power, high speed device with high Z input pulldown resistors and open emitter outputs.

### LOGIC DIAGRAM



### FEATURES

- FAST PROPAGATION DELAY  
= 4.0 ns TYP ADDRESS TO OUTPUT  
= 4.5 ns TYP ENABLE OR DATA TO OUTPUT
- LOW POWER DISSIPATION = 310 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE EIGHT 50 Ω LINES
- TRUE PARALLEL DECODER – ELIMINATES UNEQUAL DELAY TIMES
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- OPEN EMITTER OUTPUTS
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

### APPLICATIONS

- Dual 1 line to 4 line Demultiplexer
- Crossbar Switch Applications
- High Fanout 1 of 4 Decoder
- Memory Chip Select Decoder

### TRUTH TABLE

INPUTS				OUTPUTS			
$\overline{E0}$	A1	A0	DAIN	DA0	DA1	DA2	DA3
L	L	L	L	L	H	H	H
L	L	L	H	H	H	H	H
L	L	H	L	H	L	H	H
L	L	H	H	H	H	H	H
L	H	L	L	H	H	L	H
L	H	L	H	H	H	H	H
L	H	H	L	H	H	H	L
L	H	H	H	H	H	H	H
H	φ	φ	φ	H	H	H	H

DB is Similar. φ = Don't Care.

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin CERDIP

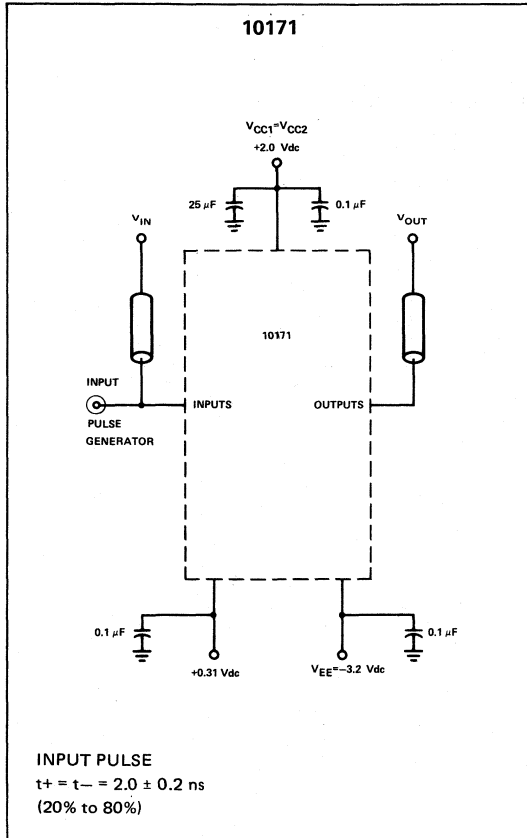
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

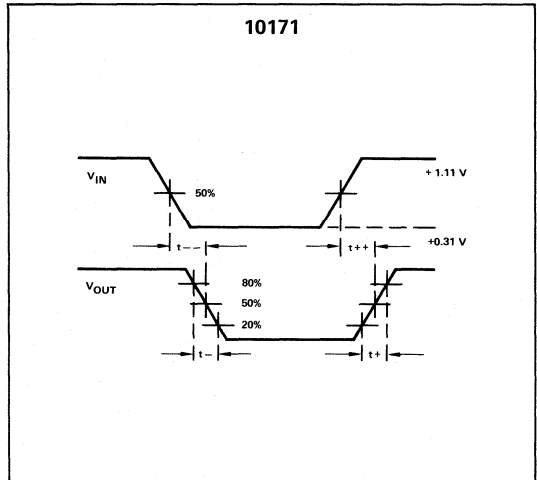
Characteristic	Symbol	Pin Under Test	10171 Test Limits												TEST VOLTAGE VALUES					Unit	(V <sub>CC</sub> ) Gnd				
			-30°C						+25°C			+85°C			(Volts)										
			Min	Max	Min	Typ	Max	Min	Max	Min	Max	V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IHA</sub> max	V <sub>EE</sub>									
			TEST VOLTAGE APPLIED TO PINS LISTED BELOW:																						
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	60	-	-	-	-	-	-	-	-	8	1,16	mAdc	2,7,9,14,15	-	-	-	-	-	8	1,16
Input Current	I <sub>inH</sub>	14	-	-	-	-	265	-	-	-	-	-	-	-	8	1,16	μAdc	14	-	-	-	-	-	8	1,16
	I <sub>inL</sub>	14	-	-	0.5	-	-	-	-	-	-	-	-	-	8	1,16	μAdc	-	14	-	-	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	13	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	14	-	-	-	8	1,16	Vdc	14	-	-	-	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	13	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	15	-	-	-	8	1,16	Vdc	15	-	-	-	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	13	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	14	-	8	1,16	Vdc	-	-	14	-	-	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	13	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	15	-	8	1,16	Vdc	-	-	15	-	-	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	13	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	-	-	14	8	1,16	Vdc	-	-	-	14	-	-	8	1,16
Switching Times * (50-ohm load)													Pulse In	Pulse Out	-3.2 V	+2.0 V									
Propagation Delay	t <sub>p+ 13+</sub>	13	-	-	-	4.0	-	-	-	ns	-	-	9	13	8	1,16									
	t <sub>p- 13-</sub>	13	-	-	-	4.0	-	-	-																
Rise Time (20% to 80%)	t <sub>13+</sub>	13	-	-	-	2.0	-	-	-																
Fall Time (20% to 80%)	t <sub>13-</sub>	13	-	-	-	2.0	-	-	-																

\*Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 6 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10172F: -30 to +85°C, CERDIP

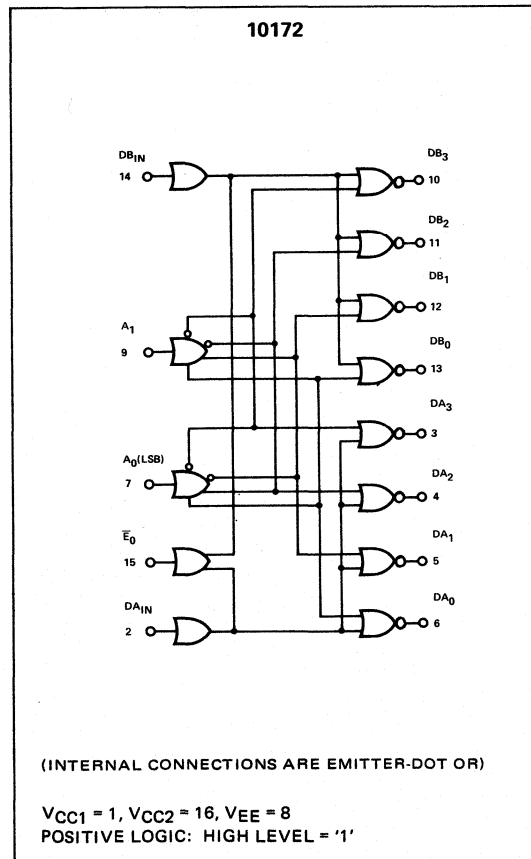
DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10172 is a binary coded 2 line to 4 line decoder/demultiplexer. Outputs are normally low with the selected outputs going high. The enable input when high forces all eight outputs low. Each data input when low forces its four outputs low. Hence, when using as a decoder the data inputs should be connected to a logic "1" level. Data paths are non-inverting.

The 10172 is a true parallel decoder using internal emitter dotting techniques. Hence it eliminates unequal delay times found in other decoders. The 10172 is a low power, high speed device with high Z input pulldown resistors and open emitter outputs.

### LOGIC DIAGRAM



### FEATURES

- FAST PROPAGATION DELAY  
= 4.0 ns TYP ADDRESS TO OUTPUT  
= 4.5 ns TYP ENABLE OR DATA TO OUTPUT
- LOW POWER DISSIPATION = 310 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY – CAN DRIVE EIGHT 50 Ω LINES
- TRUE PARALLEL DECODER – ELIMINATES UNEQUAL DELAY TIMES
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: VEE = -5.2 V ±5% RECOMMENDED
- HIGH Z INPUTS – INTERNAL 50 kΩ PULLDOWNS
- OPEN EMITTER OUTPUTS
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

### APPLICATIONS

- Dual 1 line to 4 line Demultiplexer
- Crossbar Switch Applications
- High Fanout 1 of 4 Decoder
- Memory Chip Select Decoding

### TRUTH TABLE

INPUTS				OUTPUTS			
E0	A1	A0	DA1N	DA0	DA1	DA2	DA3
L	L	L	H	H	L	L	L
L	L	L	L	L	L	L	L
L	L	H	H	L	H	L	L
L	L	H	L	L	L	L	L
L	H	L	H	L	L	H	L
L	H	L	L	L	L	L	L
L	H	H	H	L	L	L	H
L	H	H	L	L	L	L	L
H	φ	φ	φ	L	L	L	L

DB is Similar. φ = Don't Care

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16-Pin CERDIP

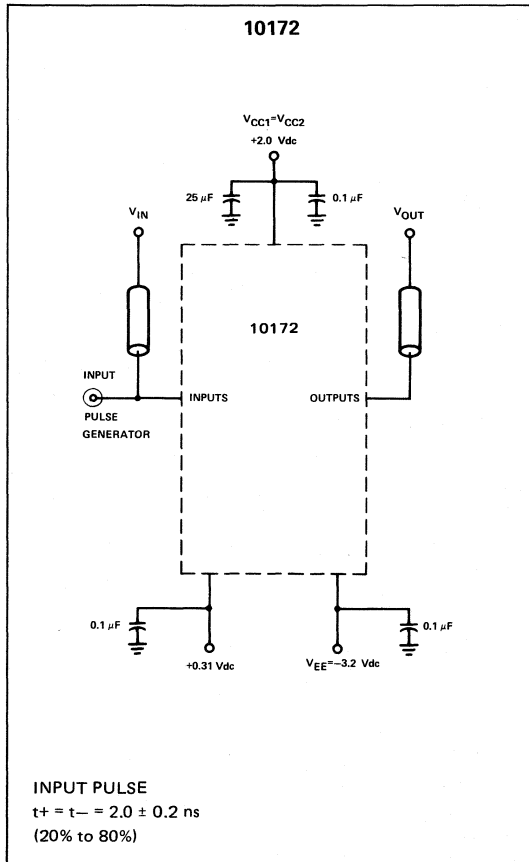
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

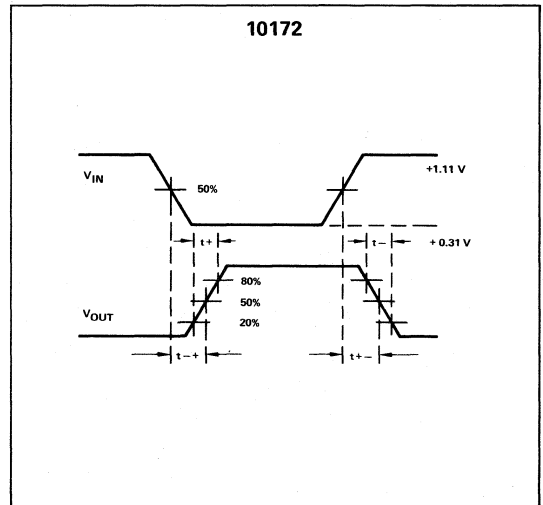
Characteristic	Symbol	Pin Under Test	10172 Test Limits						Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					V <sub>CC</sub> Gnd	
			-30° C		+25° C		+85° C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IILA</sub> max	V <sub>EE</sub>		
			Min	Max	Min	Max	Min	Max								
Power Supply Drain Current	I <sub>E</sub>	8	-	-	-	60	75	-	-	mAdc	-	-	-	-	8	1,16
Input Current	I <sub>inH</sub>	14	-	-	-	-	265	-	-	μAdc	14	-	-	-	8	1,16
	I <sub>inL</sub>	14	-	-	0.5	-	-	-	-	μAdc	-	14	-	-	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	13	-0.60	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	14	-	-	-	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	13	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	-	-	-	-	8	1,16
Output Voltage		13	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.615	Vdc	9,14	-	-	-	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	13	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	14	-	8	1,16
Logic "0" Threshold Voltage	V <sub>OLA</sub>	13	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	-	-	14	8	1,16
Threshold Voltage		13	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	-	9	-	8	1,16
Switching Times * (50-ohm load)													Pulse In	Pulse Out	-3.2 V	+2.0 V
Propagation Delay	t <sub>p+ 13-</sub> t <sub>p- 13+</sub>	13	-	-	-	4.0	-	-	-	ns	-	-	9	13	8	1,16
Rise Time (20% to 80%)	t <sub>r</sub>	13	-	-	-	2.0	-	-	-	↓	-	-	↓	↓	↓	↓
Fall Time (20% to 80%)	t <sub>f</sub>	13	-	-	-	2.0	-	-	-	↓	-	-	↓	↓	↓	↓

\*Unused outputs connected to a 50-ohm resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25° C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

10173F: -30 TO +85°C

## DIGITAL 10,000 SERIES ECL

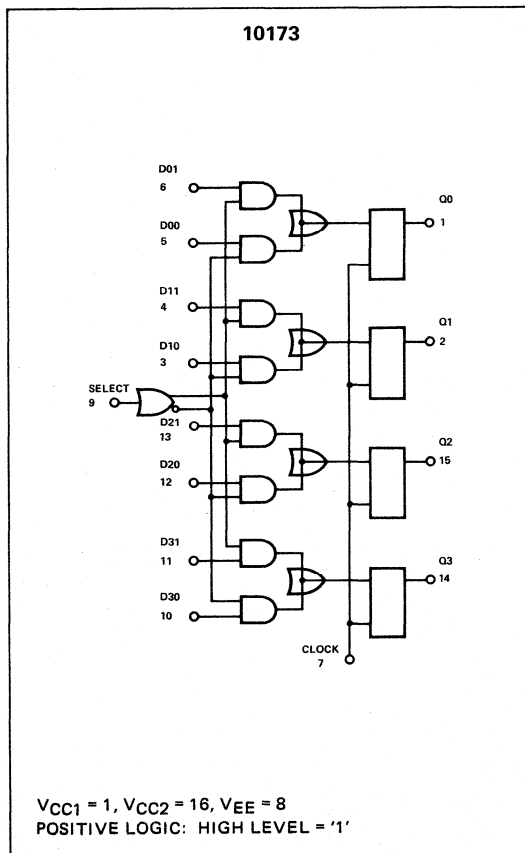
### DESCRIPTION

The 10173 is a quad clocked D-type latch with 2 to 1 data multiplexing.

Any change at the selected D input will be reflected at the output while the clock is low. The outputs are latched on the positive transition of the clock. While the clock is in the high state, a change in the information present at the data or select inputs will not affect the output information.

When the select input is false, the D<sub>n0</sub> inputs are selected and when select is true the D<sub>n1</sub> inputs are selected. As a quad 2-Input Multiplexer, with the added feature of a latch output, the 10173 provides the data select and store function in the same package. The result is a savings in system delay and package count.

### LOGIC DIAGRAM



### FEATURES

- SIMULTANEOUS MULTIPLEXING AND LATCHING FUNCTION IMPROVES SYSTEM PERFORMANCE
- QUAD LATCH AND MULTIPLEXER ON ONE CHIP INCREASES SYSTEM DENSITY
- FAST PROPAGATION DELAY  
= 2.5 ns TYP (DATA TO OUTPUT)  
= 3.7 ns TYP (SELECT TO OUTPUT)  
= 4.3 ns TYP (CLOCK TO OUTPUT)
- LOW POWER DISSIPATION = 325 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY - CAN DRIVE 50 Ω LINES
- HIGH Z INPUTS - INTERNAL 50 kΩ PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: V<sub>EE</sub> = -5.2 V ±5% RECOMMENDED
- OPEN EMITTER OUTPUTS - ALLOW WIRE OR AND DATA BUSSING

### APPLICATIONS

COMBINED MULTIPLEXER - REGISTER FOR:

- high speed central processors
- high speed peripherals
- high speed minicomputers
- communication systems
- instrumentation

### TRUTH TABLE

D <sub>n</sub>	C	Q <sub>n</sub> (N + 1)
L	L	L
H	L	H
φ	H	Q <sub>n</sub> (N)

$$D_n = \bar{S} \cdot D_{n0} + S \cdot D_{n1}$$

φ = Don't Care.

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16 Pin CERDIP

**ELECTRICAL CHARACTERISTICS**

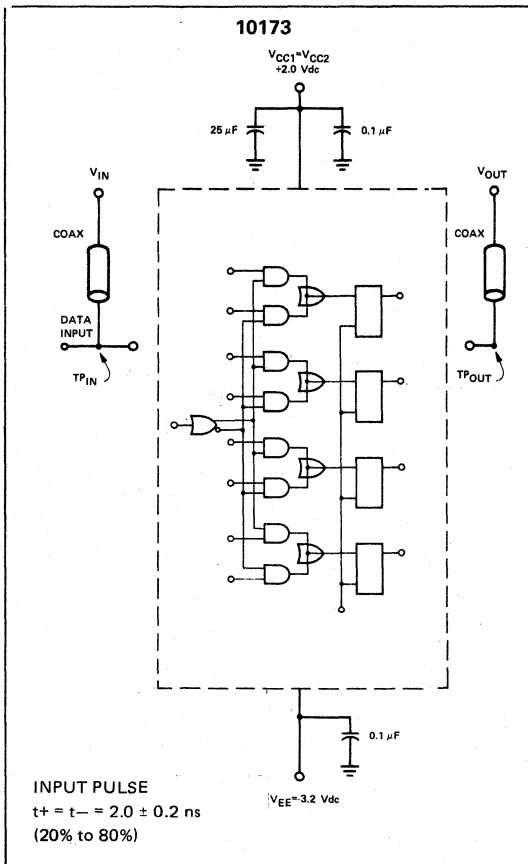
(at Listed Voltages and Ambient Temperatures).

② Test Temperature		TEST VOLTAGE VALUES (Volts)				
		V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>
-30° C		-0.890	-1.890	-1.205	-1.500	-5.2
+25° C		-0.810	-1.850	-1.105	-1.475	-5.2
+85° C		-0.700	-1.625	-1.035	-1.440	-5.2

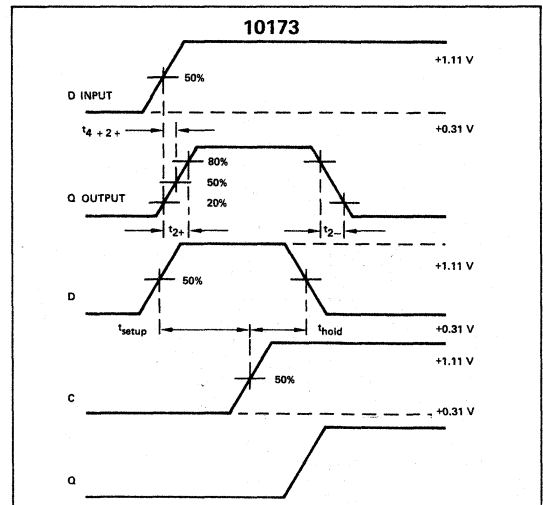
Characteristic	Symbol	Pin Under Test	10173 Test Limits						Unit	TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					Gnd	
			-30° C		+25° C		+85° C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>ILA</sub> max	V <sub>EE</sub>		
			Min	Max	Min	Max	Min	Max								
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	78	—	—	mAdc	7.9	—	—	—	8	16	
Input Current	I <sub>in H</sub>	5	—	—	—	290	—	—	μAdc	5	—	—	—	8	16	
		6	—	—	—	220	—	—		6	—	—	—			
		7	—	—	—	290	—	—		7	—	—	—			
		9	—	—	—	220	—	—		9	—	—	—			
Logic "1" Output Voltage	V <sub>OH</sub>	4*	—	—	0.50	—	—	—	μAdc	—	4	—	—	8	16	
		2	-1.060	-0.890	-0.960	-0.810	-0.890	-0.700		Vdc	4	7.9	—	—	8	16
Logic "0" Output Voltage	V <sub>OL</sub>	2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	—	4.7, 9	—	—	8	16	
		2	-1.890	-1.675	-1.850	-1.650	-1.825	-1.615	Vdc	9	3.7	—	—	8	16	
Logic "1" Threshold Voltage	V <sub>OHA</sub>	2	-1.080	—	-0.980	—	-0.910	—	Vdc	—	7.9	4	—	8	16	
		2	-1.080	—	-0.980	—	-0.910	—	Vdc	9	7	3	—	8	16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	2	—	-1.655	—	-1.630	—	-1.595	Vdc	—	7.9	7	—	4	8	16
		2	—	-1.655	—	-1.630	—	-1.595	Vdc	9	7	—	3	8	16	
Switching Times (50-ohm load) (See Figure 1)					Typ	Max				+1.11 V	+0.31 V	Pulse In	Pulse Out	-3.2 V	+2.0 V	
Propagation Delay	Data	t <sub>4+ 2+</sub>	2	—	—	2.5	—	—	ns	9	7	4	2	8	16	
	Clock	t <sub>7- 2+</sub>	2	—	—	4.3	—	—	ns	4.9	—	7	4	8	16	
	Select	t <sub>9+ 2+</sub>	2	—	—	3.7	—	—	ns	4	7	9	2	8	16	
Setup Time	Data	t <sub>setup</sub>	2	—	—	1.5	—	—	ns	—	7.9	4	2	8	16	
	Select	t <sub>setup</sub>	2	—	—	2.5	—	—	ns	3	7	9	2	8	16	
Hold Time	Data	t <sub>hold</sub>	2	—	—	0.0	—	—	ns	—	7.9	4	2	8	16	
	Select	t <sub>hold</sub>	2	—	—	-0.5	—	—	ns	3	7	9	2	8	16	
Rise Time (20% to 80%)		t <sub>2+</sub>	2	—	—	2.0	—	—	ns	—	7.9	4	2	8	16	
Fall Time (20% to 80%)		t <sub>2-</sub>	2	—	—	2.0	—	—	ns	—	7.9	4	2	8	16	

\*All other inputs tested in the same manner

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25° C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 6 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

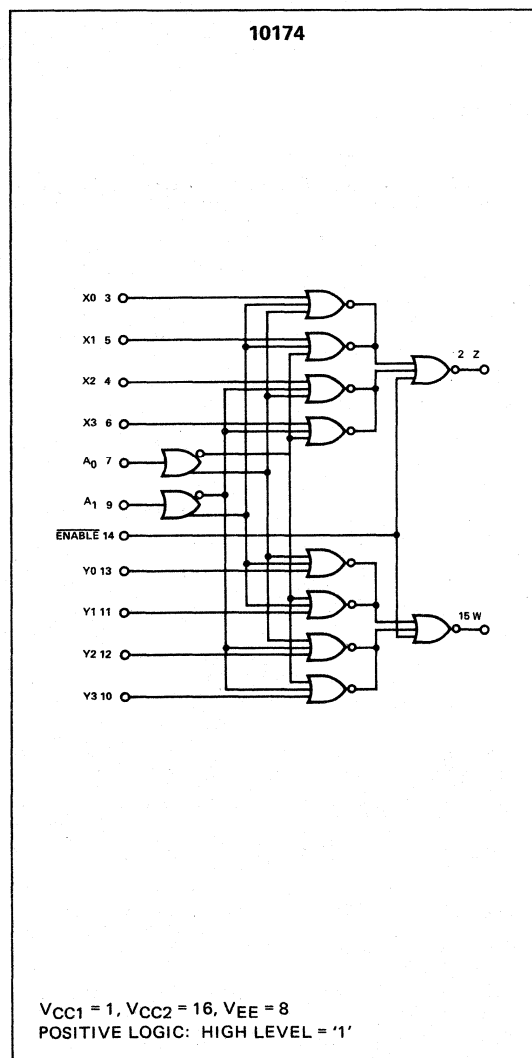
10174F: -30 to +85°C, CERDIP

DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10174 is a high speed dual channel multiplexer with output enable capability. The select inputs determine one of four active data inputs for each multiplexer. An output enable forces both outputs low when in the high state. The enable is also useful in wire-ORing several multiplexers to achieve additional channel capability. Delay from data input to output is typically 3.5 nanoseconds.

### LOGIC DIAGRAM



### FEATURES

- FAST PROPAGATION DELAY  
= 3.5 ns TYP DATA TO OUTPUT  
= 5.0 ns TYP ADDRESS TO OUTPUT  
= 2.0 ns TYP ENABLE TO OUTPUT
- OUTPUT ENABLE TO PERMIT OUTPUT BUSSING
- LOW POWER DISSIPATION = 290 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY - CAN DRIVE TWO 50 Ω LINES
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS: VEE = -5.2 V ±5% RECOMMENDED
- MEETS ECL 10,000 SERIES STANDARD INTERFACE SPECIFICATIONS

### APPLICATIONS

- Dual 4 to 1 Multiplexer
- Dual 4 to 1 Data Selector
- Cross Bar Switch Applications

### TRUTH TABLE

ENABLE	ADDRESS INPUTS		OUTPUTS		
	$\bar{E}$	A1	A0	Z	W
H	H	$\phi$	$\phi$	L	L
L	L	L	L	X0	Y0
L	L	L	H	X1	Y1
L	L	H	L	X2	Y2
L	L	H	H	X3	Y3

$\phi$  = Don't Care.

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 16 Pin CERDIP



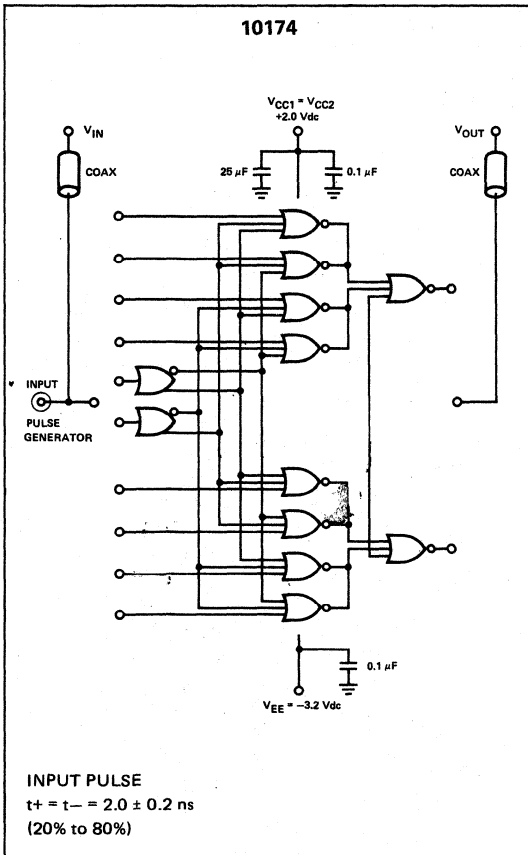
**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

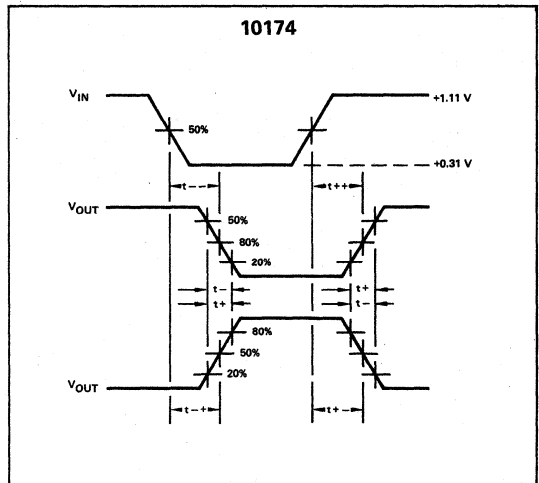
Characteristic	Symbol	Pin Under Test	10174 Test Limits									TEST VOLTAGE APPLIED TO PINS LISTED BELOW:					(V <sub>CC</sub> ) Gnd
			-30°C			+25°C			+85°C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>IILA</sub> max	V <sub>EE</sub>	
			Min	Max	Typ	Max	Min	Max	Unit								
			TEST VOLTAGE VALUES (Volts)														
Power Supply Drain Current	I <sub>E</sub>	8	—	—	—	55	73	—	—	—	mAdc	—	—	—	—	8	1,16
Input Current	I <sub>inH</sub>	4	—	—	—	220	—	—	—	—	μAdc	4	—	—	—	8	1,16
		14	—	—	—	330	—	—	—	—	—	14	—	—	—	8	1,16
	I <sub>inL</sub>	4	—	—	0.5	—	—	—	—	—	μAdc	—	4	—	—	8	1,16
Logic "1" Output Voltage	V <sub>OH</sub>	15	-1.060	-0.890	-0.960	—	-0.810	-0.890	-0.700	Vdc	13	—	—	—	—	8	1,16
Logic "0" Output Voltage	V <sub>OL</sub>	15	-1.890	-1.675	-1.850	—	-1.650	-1.825	-1.615	Vdc	14	—	—	—	—	8	1,16
Logic "1" Threshold Voltage	V <sub>OHA</sub>	15	-1.080	—	-0.980	—	—	-0.910	—	Vdc	—	—	—	14	8	1,16	
Logic "0" Threshold Voltage	V <sub>OLA</sub>	15	—	-1.655	—	—	-1.630	—	-1.595	Vdc	—	—	—	14	8	1,16	
Switching Times* (50 Ω load)											+1.11 V		Pulse In	Pulse Out	-3.2 V	+2.0 V	
Propagation Delay	t <sub>13+15+</sub>	15	—	—	—	3.5	—	—	—	ns	—	—	13	15	8	1,16	
	t <sub>13-15-</sub>	15	—	—	—	3.5	—	—	—	—	—	—	13	—	—	—	
	t <sub>7+15-</sub>	15	—	—	—	5.0	—	—	—	—	11	—	7	—	—	—	
	t <sub>7-15+</sub>	15	—	—	—	5.0	—	—	—	—	11	—	7	—	—	—	
	t <sub>14+15-</sub>	15	—	—	—	2.0	—	—	—	—	—	—	14	—	—	—	
	t <sub>14-15+</sub>	15	—	—	—	2.0	—	—	—	—	—	—	14	—	—	—	
Rise Time (20% to 80%)	t <sub>r</sub>	15	—	—	—	2.0	—	—	—	—	—	—	14	—	—	—	
Fall Time (20% to 80%)	t <sub>f</sub>	15	—	—	—	2.0	—	—	—	—	—	—	14	—	—	—	

\*Unused outputs connected to a 50 Ω resistor to ground.

**SWITCHING TIME TEST CIRCUIT**



**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is maintained. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>IN</sub> to input pin and TP<sub>OUT</sub> to output pin. A 50-ohm termination to ground is located in each scope channel input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

## ADVANCE INFORMATION TO BE ANNOUNCED

10181F: -30 to +85°C, CERDIP

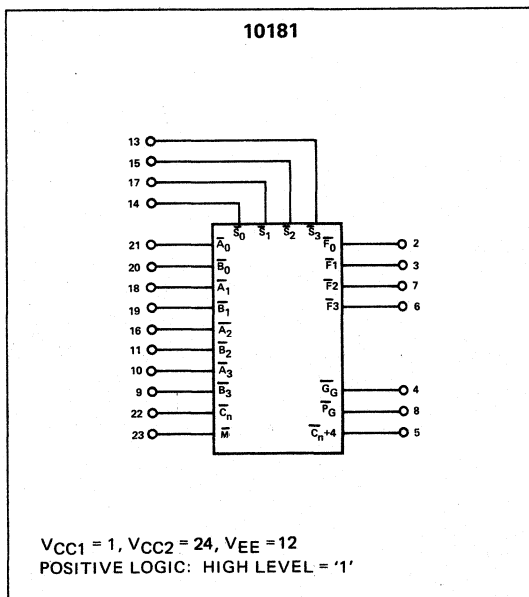
DIGITAL 10,000 SERIES ECL

### DESCRIPTION

The 10181 is an extremely versatile high speed arithmetic logic unit capable of performing 16 logic operations and 16 arithmetic functions on two four-bit words. Using advanced circuit design techniques and double layer metalization the 10181 represents the state-of-the-art in standard ECL/LSI functions. As a result, the 10181 has the same power dissipation as the comparable TTL function, while increasing the speed of operation by a factor of 4.

The  $\bar{M}$  input selects the arithmetic or logic mode of operation on 2 four-bit words. The desired arithmetic or logic function is selected by applying the appropriate binary word to the select inputs ( $\bar{S}_0$  thru  $\bar{S}_3$ ). Full internal carry is incorporated for ripple-through operation. Group carry propagate ( $P_G$ ) and carry generate ( $G_G$ ) are provided to allow fast addition of very long words using a second order look-ahead in conjunction with the 10179 full look-ahead carry block. The internal carry is enabled when the mode control input ( $M$ ) has a low-level voltage applied (arithmetic operation). Full addition of two 32-bit words, with carry in and carry out can be performed in 18 ns. All inputs have 50k $\Omega$  internal pulldown resistors, and outputs are all open emitters for versatility in interconnect techniques.

### BLOCK DIAGRAM



### FEATURES

- FAST PROPAGATION DELAYS:
  - = 3.1 ns TYP ( $C_n$  TO  $C_{n+4}$ )
  - = 5.0 ns TYP ( $\bar{C}_n$  TO  $\bar{F}_1$ )
  - = 7.0 ns TYP ( $\bar{A}_1, \bar{B}_1$  TO  $\bar{F}_1$ )
  - = 5.0 ns TYP ( $\bar{A}_1$  TO  $C_{n+4}$ )
- 16 LOGIC OPERATIONS
- 16 ARITHMETIC OPERATIONS
- POWER DISSIPATION = 600 mW/PACKAGE TYP (NO LOAD)
- HIGH Z INPUTS – INTERNAL 50 k $\Omega$  PULLDOWNS
- HIGH IMMUNITY FROM POWER SUPPLY VARIATIONS:  $V_{EE} = -5.2 V \pm 5\%$  RECOMMENDED
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

### PACKAGE TYPE

- F: 24-Pin CERDIP

### FUNCTIONAL TRUTH TABLE

POSITIVE LOGIC

Function Select $\bar{S}_3 \bar{S}_2 \bar{S}_1 \bar{S}_0$	Logic Functions	Arithmetic Operation
	$\bar{M}$ is High F	$\bar{M}$ is Low $\bar{C}_n$ of LSB must be High $\bar{F}^*$
L L L L	$\bar{F} = A$	F = A minus 1
L L L H	$\bar{F} = A + B$	F = A plus (A + $\bar{B}$ )
L L H L	$\bar{F} = A + \bar{B}$	F = A plus (A + B)
L L H H	$\bar{F} = \text{Logical "1"}$	F = A times 2
L H L L	$\bar{F} = A \cdot B$	F = (A · B) minus 1
L H L H	$\bar{F} = B$	F = (A · B) plus (A + $\bar{B}$ )
L H H L	$\bar{F} = A \oplus B$	F = A plus B
L H H H	$\bar{F} = \bar{A} + B$	F = A plus (A · B)
H L L L	$\bar{F} = A \cdot \bar{B}$	F = (A · $\bar{B}$ ) minus 1
H L L H	$\bar{F} = A \oplus \bar{B}$	F = A minus B minus 1
H L H L	$\bar{F} = \bar{B}$	F = (A · $\bar{B}$ ) plus (A + B)
H L H H	$\bar{F} = \bar{A} + \bar{B}$	F = (A · $\bar{B}$ ) plus A
H H L L	$\bar{F} = \text{Logical "0"}$	F = minus 1 (two's complement)
H H L H	$\bar{F} = \bar{A} \cdot B$	F = (A + $\bar{B}$ ) plus 0
H H H L	$\bar{F} = \bar{A} \cdot \bar{B}$	F = (A + B) plus 0
H H H H	$\bar{F} = \bar{A}$	F = A plus 0

\* $\bar{F}$  outputs of ALU are one's complement of function listed below.

**ELECTRICAL CHARACTERISTICS**

(at Listed Voltages and Ambient Temperatures).

Characteristic	Symbol	Pin Under Test	10181 Test Limits						Unit	TEST VOLTAGE VALUES (Volts)					Gnd					
			-30° C		+25° C		+85° C			V <sub>IH</sub> max	V <sub>IL</sub> min	V <sub>IHA</sub> min	V <sub>VLA</sub> max	V <sub>EE</sub>						
			Min	Max	Min	Typ	Max	Min		Max										
Power Supply Drain Current	I <sub>E</sub>	12	-	-	-	-	145	-	-	mAdc	-0.890	-1.890	-1.205	-1.500	-5.2	12	1,24			
Input Current	I <sub>inH</sub>	9	-	-	-	-	245	-	-	μAdc	9	-	-	-	-	12	1,24			
		10	-	-	-	-	220	-	-		10	-	-	-	-	-	-	-		
		11	-	-	-	-	245	-	-		11	-	-	-	-	-	-	-	-	
		13	-	-	-	-	200	-	-		13	-	-	-	-	-	-	-	-	
		14	-	-	-	-	265	-	-		14	-	-	-	-	-	-	-	-	
		15	-	-	-	-	265	-	-		15	-	-	-	-	-	-	-	-	
		16	-	-	-	-	220	-	-		16	-	-	-	-	-	-	-	-	
		17	-	-	-	-	265	-	-		17	-	-	-	-	-	-	-	-	
		18	-	-	-	-	220	-	-		18	-	-	-	-	-	-	-	-	
		19	-	-	-	-	245	-	-		19	-	-	-	-	-	-	-	-	-
		20	-	-	-	-	245	-	-		20	-	-	-	-	-	-	-	-	-
		21	-	-	-	-	220	-	-		21	-	-	-	-	-	-	-	-	-
		22	-	-	-	-	290	-	-		22	-	-	-	-	-	-	-	-	-
23	-	-	-	-	200	-	-	23	-	-	-	-	-	-	-	-	-			
Input Leakage Current	I <sub>inL</sub>	9	-	-	0.5	-	-	-	-	μAdc	-	9	-	-	-	12	1,24			
10	-	-	-	-	-	-	-	-	-	-	-	10	-	-	-	-	-			
11	-	-	-	-	-	-	-	-	-	-	-	11	-	-	-	-	-			
13	-	-	-	-	-	-	-	-	-	-	-	13	-	-	-	-	-			
14	-	-	-	-	-	-	-	-	-	-	-	14	-	-	-	-	-			
15	-	-	-	-	-	-	-	-	-	-	-	15	-	-	-	-	-			
16	-	-	-	-	-	-	-	-	-	-	-	16	-	-	-	-	-			
17	-	-	-	-	-	-	-	-	-	-	-	17	-	-	-	-	-			
18	-	-	-	-	-	-	-	-	-	-	-	18	-	-	-	-	-			
19	-	-	-	-	-	-	-	-	-	-	-	19	-	-	-	-	-			
20	-	-	-	-	-	-	-	-	-	-	-	20	-	-	-	-	-			
21	-	-	-	-	-	-	-	-	-	-	-	21	-	-	-	-	-			
22	-	-	-	-	-	-	-	-	-	-	-	22	-	-	-	-	-			
23	-	-	-	-	-	-	-	-	-	-	-	23	-	-	-	-	-			
High Output Voltage	V <sub>OH</sub>	*	-1.060	-0.890	-0.960	-	-0.810	-0.890	-0.700	Vdc	*	*	-	-	-	12	1,24			
Low Output Voltage	V <sub>OL</sub>	*	-2.000	-1.675	-1.990	-	-1.650	-1.920	-1.615	Vdc	*	*	-	-	-	12	1,24			
High Threshold Voltage	V <sub>OHA</sub>	*	-1.080	-	-0.980	-	-	-0.910	-	Vdc	-	-	**	**	**	12	1,24			
Low Threshold Voltage	V <sub>OLA</sub>	*	-	-1.655	-	-	-1.630	-	-1.595	Vdc	-	-	**	**	**	12	1,24			

\*Test all input-output combinations according to Function Table.  
 \*\*For threshold level test, apply threshold input level to only one input pin at a time.

Each ECL 10,000 series has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a

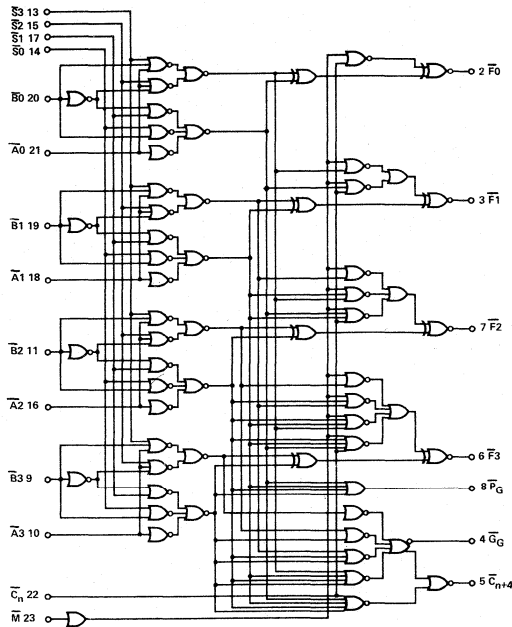
printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50-ohm resistor to -2.0 volts.

Characteristic	Symbol	Input	Output	Conditions <sup>1</sup>	AC Switching Characteristics +25° C		
					Min	Typ	Max
Propagation Delay	t <sub>++</sub>	C <sub>n</sub>	C <sub>n+4</sub>	-	-	3.1	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	3.1	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	C <sub>n</sub>	F1	M is Low	-	4.9	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	4.9	↓
Propagation Delay	t <sub>+-</sub>	C <sub>n</sub>	F1	-	-	5.0	↓
Rise Time	t <sub>+-</sub>	-	-	-	-	2.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>++</sub>	A1	F1	-	-	7.0	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	7.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	7.0	↓
Propagation Delay	t <sub>+-</sub>	A1	P <sub>G</sub>	-	-	3.0	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	3.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>++</sub>	A1	G <sub>G</sub>	-	-	4.0	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	A1	C <sub>n+4</sub>	-	-	5.4	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	4.4	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>++</sub>	B1	F1	S1 and S2 High, S0 or S3 Low	-	7.5	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	8.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	7.5	↓
Propagation Delay	t <sub>+-</sub>	A1	P <sub>G</sub>	-	-	3.0	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	3.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	B1	P <sub>G</sub>	S1 Low	-	4	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	4	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	B1	G <sub>G</sub>	S2 Low	-	5.2	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.7	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	B1	C <sub>n+4</sub>	S0 or S1 or S2 or S3 Low	-	5.9	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.6	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓

Characteristic	Symbol	Input	Output	Conditions <sup>1</sup>	AC Switching Characteristics +25° C		
					Min	Typ	Max
Propagation Delay	t <sub>++</sub>	B1	P <sub>G</sub>	S0 Low, S1 High	-	3.0	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	3.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>++</sub>	B1	G <sub>G</sub>	S2 High, S3 Low	-	4.0	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	B1	C <sub>n+4</sub>	S1 and S2 High, S0 or S3 Low	-	5.4	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	4.4	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>++</sub>	B1	F1	S1 or S2 Low	-	7.5	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	8.0	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	7.5	↓
Propagation Delay	t <sub>+-</sub>	B1	P <sub>G</sub>	S1 Low	-	4	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	4	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	B1	G <sub>G</sub>	S2 Low	-	5.2	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.7	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓
Propagation Delay	t <sub>+-</sub>	B1	C <sub>n+4</sub>	S0 or S1 or S2 or S3 Low	-	5.9	ns
Rise Time	t <sub>+-</sub>	-	-	-	-	5.6	↓
Fall Time	t <sub>-+</sub>	-	-	-	-	2.0	↓

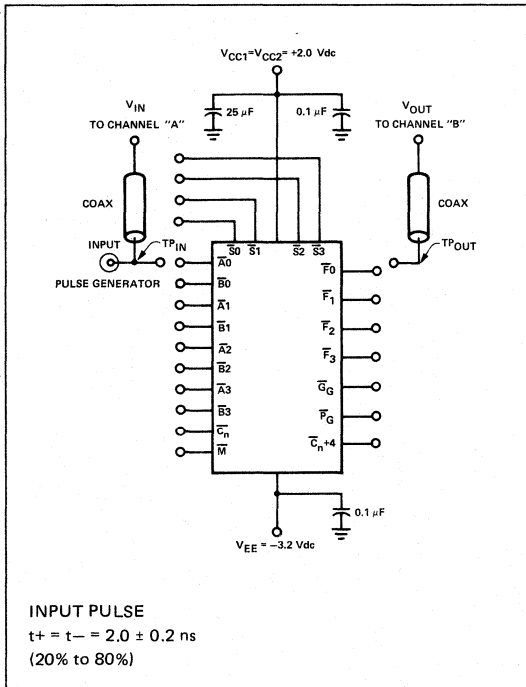
t<sub>H</sub> High = +1.11 V  
 Low = +0.31 V  
 V<sub>CC1</sub> = V<sub>CC2</sub> = +2.0 Vdc = -3.2 Vdc, V<sub>EE</sub> = -3.2 Vdc

LOGIC DIAGRAM



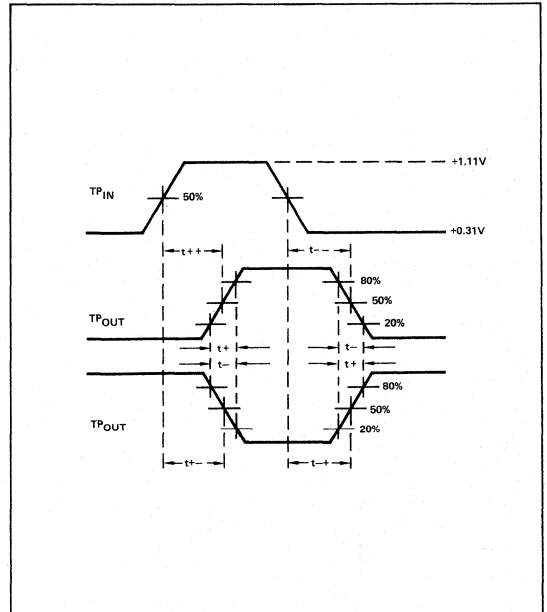
Positive logic: High Level = "1"

SWITCHING TIME TEST CIRCUIT



INPUT PULSE  
 $t_+ = t_- = 2.0 \pm 0.2 \text{ ns}$   
 (20% to 80%)

PROPAGATION DELAY WAVEFORM @ 25°C



All input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be  $< 1/4$  inch from  $TP_{IN}$  to input pin and  $TP_{OUT}$  to output pin.

10190F: -30 to +85°C, CERDIP  
DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10190 is both a general purpose ECL 10,000 series line receiver and an MST (IBM 370) to ECL translator. With the V<sub>CC</sub> Terminal (Pin 9) connected to ground, the device will accept either single-ended or differential ECL 10K signals. With V<sub>CC</sub> connected to +1.25 Volts, the device will accept MST logic levels (+0.4 and -0.4 nominal). In either case, the output of the 10190 is standard ECL 10K.

When used in the translator mode, one of the differential inputs is tied to ground and the other to the MST source. V<sub>CC</sub> is non-critical between +0.5 and +2.0 Volts.

In the ECL line receiver mode, a single ended input is accommodated by connecting the other input to an external V<sub>BB</sub> source.

## FEATURES

- HIGH SPEED; PROPAGATION DELAY = 2.5 ns Typ
- HIGH COMMON MODE NOISE REJECTION
- OUTPUT DRIVES 50 Ω LINES
- DUAL-PURPOSE
  - Quad Line Receiver (ECL-ECL)
  - Translator (MST-ECL)
- HIGH INPUT IMPEDANCE
- NON-CRITICAL V<sub>CC</sub> TOLERANCE IN TRANSLATOR MODE (0.5 to +2.0 Volts)
- OPEN EMITTER OUTPUTS
- IMMUNE TO POWER SUPPLY FAULTS
- DEFINED OUTPUT (LOW) WITH BOTH INPUTS OPEN

## APPLICATIONS

LINE RECEIVER  
MST TO ECL TRANSLATOR

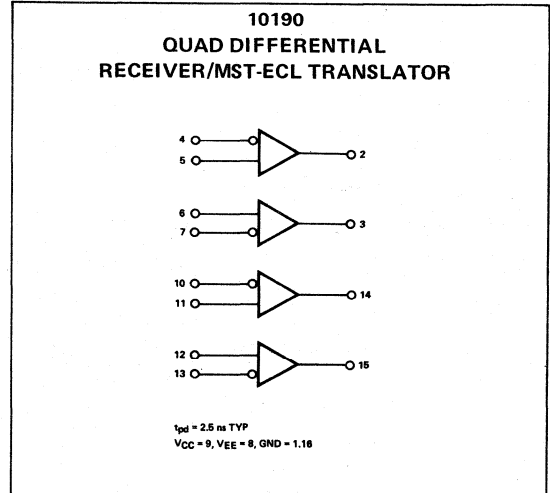
## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

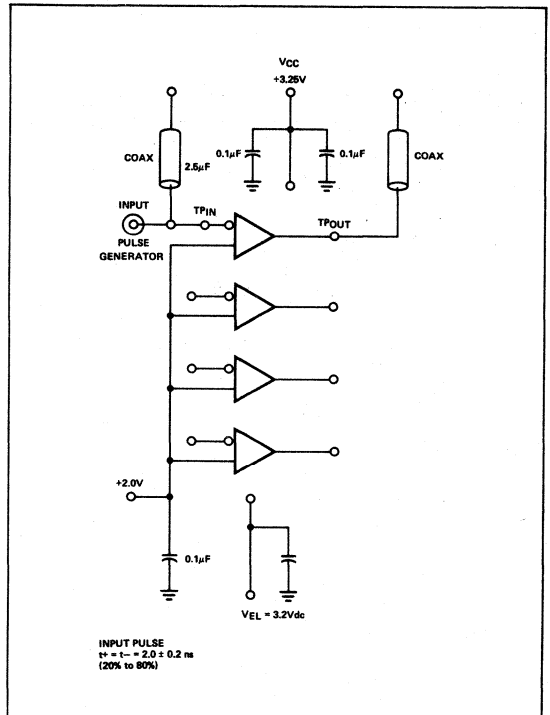
## PACKAGE TYPE

F: 16 Pin CERDIP

## LOGIC DIAGRAM



## SWITCHING TIME TEST CIRCUIT



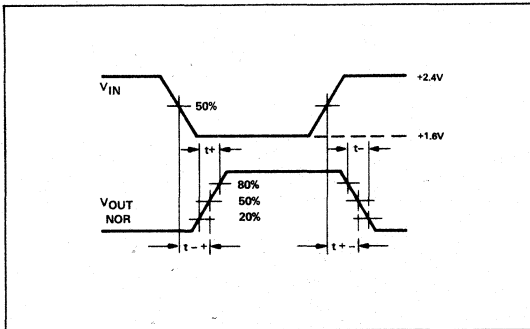
**ELECTRICAL CHARACTERISTICS** At Listed Voltages and Ambient Temperatures

CHARACTERISTICS	SYMBOL	PIN UNDER TEST	TEST LIMITS										TEST VOLTAGE VALUES					UNIT	GND	
			-30°C			+25°C			+85°C				(VOLTS)							
			MIN	MAX	TYP	MIN	MAX	MIN	MAX	MIN	MAX	VIH MAX	VIL MIN	VIHA MIN	VILA MAX	VEE				
			TEST VOLTAGE APPLIED TO PINS LISTED BELOW																	
Power Supply Current	IE	8			36	45										mA	4,7,10,13	8	5,6,11,12	
VCC Current	ICC	9			16	20										mA	4,7,10,13	8	5,6,11,12	
Input Current	IINH	4				50										μA	4	8	5,6,11,12	
Input Leakage	ICBO	4				10										μA		8,4	5,6,11,12	
Logic "1" Output Voltage	VOH	2	-1.06	-0.89	-0.96		-0.81	-0.89	-0.70						Vdc	4		8	5,6,11,12	
Logic "0" Output Voltage	VOL	2	-1.89	-1.675	-1.85		-1.65	-1.825	-1.615						Vdc	4		8	5,6,11,12	
Logic "1" Threshold Voltage	VOHA	2	-1.08		-0.98		-0.91								Vdc		4	8	5,6,11,12	
Logic "0" Threshold Voltage	VOLA	2		-1.655			-1.63		-1.595						Vdc		4	8	5,6,11,12	
Positive Common Mode	VOL	2	-1.89	-1.675	-1.85		-1.65	-1.825	-1.615						Vdc	4	4	8	5,6,11,12 9	
Negative Common Mode	VOL	2	-1.89	-1.675	-1.85		-1.65	-1.825	-1.615						Vdc	4	4	8	9	
Open Input Voltage	VOL	2		-1.675			-1.65		-1.615						Vdc		4,5,6,7,10 12,13	8	9	
Switching Times																				
Propagation Delay	t4+2-	2				2.5									ns	4	2	1,5,6,11 12,16	8	9
	t4-2+	2				2.5									ns	4	2	1,5,6,11 12,16	8	9
Rise Time (20% to 80%)	t2+					2.0									ns	4	2	1,5,6,11 12,16	8	9
Fall Time (80% to 20%)	t2-	2				2.0									ns	4	2	1,5,6,11 12,16	8	9

**NOTE**

- VCC (Pin 9) = 1.25V unless otherwise noted.
- Standard Max Ratings Apply except:  
 $V_{IN\ Max} = V_{CC} + 1\ Volt$   
 $V_{CC\ Max} = 6.0\ volts$

**PROPAGATION DELAY WAVEFORMS @ 25°C**



**NOTES:**

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 3 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.

1019F: -30 to +85°C, CERDIP  
DIGITAL 10,000 SERIES ECL

## DESCRIPTION

The 10191 is a Hex ECL to MST (IBM 370) translator. With a standard 10,000 series logic level on the input, the output responds with an identical MST logic level at the output.

In addition, the translators have a common enable line which drives all six outputs to the low state when an ECL logic "1" level is present on the line.

The 10191 is a companion device to the 10190 which is an MST to ECL translator. With these two devices, a complete, high-speed interface is available to communicate between a standard 10,000 series ECL system and a standard MST system.

## FEATURES

- HIGH SPEED; PROPAGATION DELAY = 2.2ns Typ
- SIX TRANSLATORS PER PACKAGE
- 90 OHM OUTPUT DRIVE CAPABILITY
- COMMON ENABLE INPUT
- HIGH IMPEDANCE INPUTS WITH 50K PULLDOWN RESISTORS
- OPEN EMITTER OUTPUTS

## TEMPERATURE RANGE

-30 to +85°C Operating Ambient

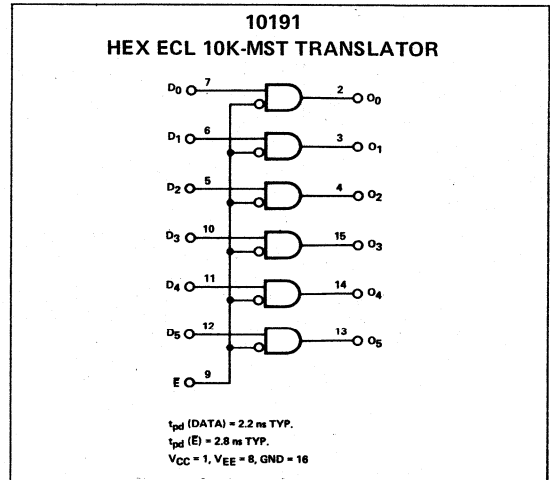
## PACKAGE TYPE

F: 16 Pin CERDIP

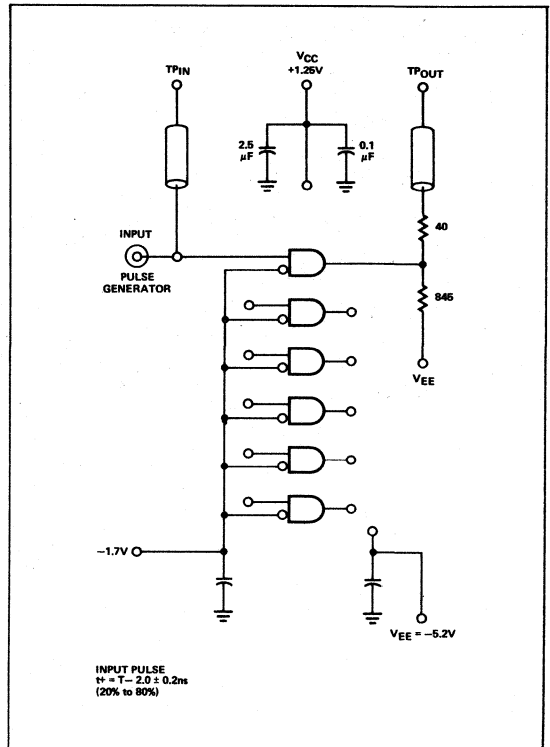
## TRUTH TABLE

$\bar{E}$	$D_n$	$O_n$
0	0	0
0	1	1
1	X	0

## LOGIC DIAGRAM



## SWITCHING TIME TEST CIRCUIT



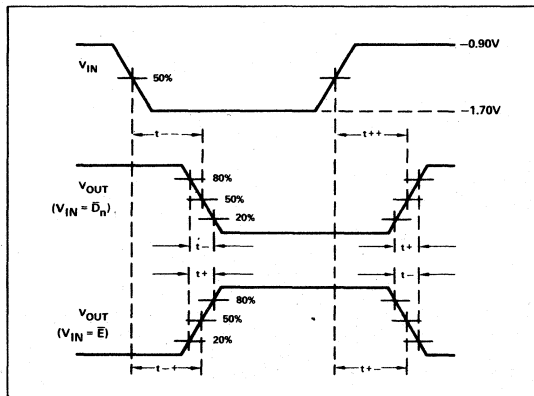
ELECTRICAL CHARACTERISTICS At Listed Voltages and Ambient Temperatures

CHARACTERISTICS	SYMBOL	PIN UNDER TEST	TEST LIMITS						UNIT	TEST VOLTAGE VALUES (VOLTS)					GND			
			0°C			+25°C				+75°C		V <sub>IH</sub> MAX	V <sub>IL</sub> MIN	V <sub>IH</sub> MIN		V <sub>IH</sub> MAX	V <sub>EE</sub>	
			MIN	MAX	MIN	TYP	MAX	MIN		MAX								
			TEST VOLTAGE APPLIED TO PINS LISTED BELOW															
Power Supply Current	I <sub>EE</sub> I <sub>CC</sub> (1)	8 1				30 18	38 23			mA mA	9 9				8 8	16 16		
Input Current	I <sub>I</sub> NH	7					245			μA	7				8	16		
	I <sub>I</sub> NH	9					265			μA	9				8	16		
	I <sub>I</sub> NL	7		0.5						μA		7			8	16		
	I <sub>I</sub> NL	9		0.5						μA		9			8	16		
High Output Voltage @ V <sub>CC</sub> = 1.30 Volts	V <sub>OH</sub> MAX	2		0.465			0.490		0.570	Vdc	7	9			8	16		
Low Output Voltage @ V <sub>CC</sub> = 1.20 Volts	V <sub>OL</sub>	2	0.265 (See note 2)	-0.345	0.310 (See note 2)		-0.330		-0.300	Vdc	7	9			8	16		
High Threshold Voltage @ V <sub>CC</sub> = 1.30 Volts	V <sub>OHA</sub>	2	0.240		0.285				0.345	Vdc		9	7		8	16		
Low Threshold Voltage @ V <sub>CC</sub> = 1.20 Volts	V <sub>OLA</sub>	2		-0.320			-0.320		-0.275	Vdc		9		7	8	16		
Switching Times	Propagation Delay	t <sub>7+2+</sub> t <sub>7-2-</sub> t <sub>9+2-</sub> t <sub>9-2+</sub>									ns	Pulse In	Pulse Out	-1.7V	-0.9V			
							2.2						7	2	9		8	16
							2.2						7	2	9		8	16
							2.8						9	2		7	8	16
Rise Time (20% to 80%)	Fall Time (80% to 20%)	t <sub>2+</sub> t <sub>2-</sub>									ns							
							2.5						7	2	9		8	16

NOTE

- V<sub>CC</sub> (Pin 1) = 1.25V unless otherwise noted. Given limits exclude overload current.
- V<sub>OL</sub> (min) is determined by load network (approx -0.500 volts with 845Ω to V<sub>CC</sub> and 90Ω to ground).

PROPAGATION DELAY WAVEFORMS @ 25°C



NOTES:

- Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Voltage levels will shift approximately 4 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to 2.0 volts.
- For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be < 1/4 inch from TP<sub>in</sub> to input pin and TP<sub>out</sub> to output pin. A 50-ohm termination to ground is located in each scope input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.



### ADVANCE INFORMATION TO BE ANNOUNCED

10210 B, F, 10211 B, F 10212 B, F: -30 to +85°C

### DIGITAL 10,000 SERIES ECL

#### DESCRIPTION

The 10210/10211/10212 are designed to drive up to six transmission lines simultaneously. The multiple outputs of these devices also allow the wire-“OR”ing of several levels of gating for minimization of gate and package count.

Three logic functions are available:

- 10210 – Triple OR outputs
- 10211 – Triple NOR outputs
- 10212 – Two NOR/One OR Outputs

The 10210/10211/10212 are high performance versions of the 10110/10111/10112.

The ability to control three parallel lines with minimum propagation delay from a single point makes the 10210/10211/10212 particularly useful in clock distribution applications where minimum clock skew is desired. The 10212 is particularly useful as a clock amplifier on a board using clock signals with both polarities.

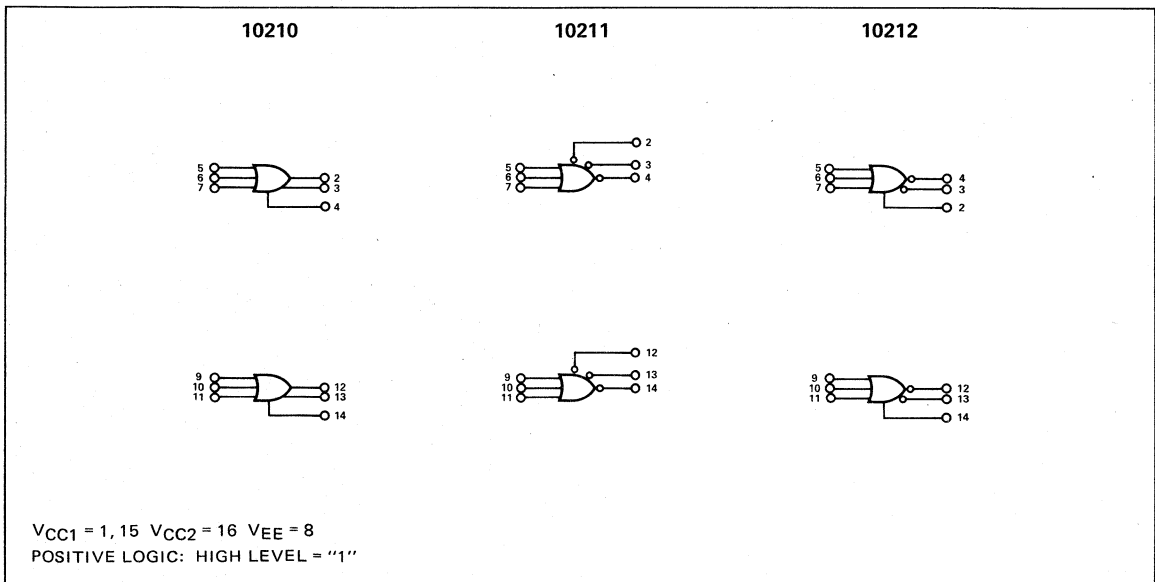
#### TEMPERATURE RANGE

- -30 to +85°C Operating Ambient

#### PACKAGE TYPES

- B: 16-Pin Silicone Dip
- F: 16-Pin CERDIP

#### LOGIC DIAGRAMS



#### FEATURES

- FAST PROPAGATION DELAY = 1.7 ns TYP. (ALL OUTPUTS LOADED)
- POWER DISSIPATION = 150 mW/PACKAGE TYP. (NO LOAD)
- VERY HIGH FANOUT CAPABILITY – CAN DRIVE SIX 50 Ω LINES
- INTERNAL 50 kΩ PULLDOWN RESISTORS
- OPEN EMITTERS FOR BUSSING AND LOGIC CAPABILITY

#### ELECTRICAL CHARACTERISTICS

Conditions;  $T_A = 25^\circ\text{C}$ ,  $V_{EE} = -5.2\text{ V} \pm 1\%$

1.  $I_E = 38\text{ mA dc max.}$

2.  $I_{inH} = 425\ \mu\text{A dc max.}$

Conditions:  $T_A = 25^\circ\text{C}$ ,  $V_{CC} = +2.0\text{ V} \pm 1\%$ ,  
 $V_{EE} = -3.2\text{ V} \pm 1\%$ , 50 Ω loads

3.  $t_{pd} = 1.7\text{ ns typ.}$

4.  $t_r, t_f = 1.5\text{ ns typ. (20\% to 80\%)}$

**Other Products To Be Announced**

10103	Quad OR Gate
10108	Dual AND Gate
10129	Quad Buss Receiver
10144	256x1 RAM
10165	Priority Encoder
10175	Quint Latch
10179	Carry Circuit
10192	Quad Buss Driver
10216	High Performance Triple Differential OR/NOR Line Receiver
10231	High Performance Dual D-Type MS Flip-Flop





**signotice**

LINEAR  
PRODUCT  
SPECIFICATIONS

**6**



## LINEAR FUNCTIONAL INDEX

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EXPLANATION

The following table has been presented to assist the designer in selecting the optimum device for his application. For the majority of applications, the primary considerations are "Input Bias Current" and "Offset Voltage". For additional specifications refer to the appropriate device data page.

DEVICE APPLICATIONS

INPUT CURRENT (nA)		SIGNETICS NUMBER	PACKAGE TYPE
MAXIMUM	TYPICAL		
0.030	0.005	SU536	T
0.100	0.030	NE536	T
0.200	0.100	$\mu$ A740	T
2.0	0.100	$\mu$ A740C	T
2.0	0.8	LM108	T
2.0	0.8	LM108A	T
7.0	1.5	LM308	T
7.0	1.5	LM308A	T
15.0	8.0	S5556 (MC1556)	T
30.0	15.0	N5556 (MC1456)	T, V
75.0	30.0	LM101A	T
75.0	30.0	LM107	T
250.0	70.0	LM301A	T, V
500.0	80.0	$\mu$ A748	T
500.0	80.0	$\mu$ A748C	A, T, V
500.0	120.0	LM101	T
500.0	200.0	$\mu$ A709	T
500.0	200.0	$\mu$ A741C	A, T, V
500.0	200.0	$\mu$ A741	A, T, V
500.0	200.0	SE531	T
1500.0	250.0	LM201	A, T, V
1500.0	300.0	$\mu$ A709	A, T, V
1500.0	400.0	NE531	T, V
OFFSET VOLTAGE (mV)			
MAXIMUM	TYPICAL		
0.5	0.3	LM108A	T
0.5	0.3	LM308A	T
2.0	0.7	LM101	T
2.0	0.7	LM107	T
2.0	0.7	LM108	T
5.0	1.0	LM101	T
5.0	1.0	$\mu$ A709	T
5.0	1.0	$\mu$ A741	T
5.0	1.0	$\mu$ A748	T
5.0	2.0	NE531	T
5.0	2.0	S5556 (MC1556)	T
6.0	1.0	$\mu$ A741C	A, T, V
5.0	2.0	NE531	T, V
6.0	2.0	$\mu$ A748C	A, T, V
7.5	1.6	LM201	A, T, V
7.5	2.0	LM301	T, V
7.5	2.0	LM308	T
7.5	2.0	$\mu$ A709C	A, T, V
10.0	4.0	N5556 (MC1456)	T, V
20.0	10.00	$\mu$ A740	T
20.0	17.5	SU536	T
90.0	30.0	NE536	T
90.0	30.0	$\mu$ A740C	T

COMMERCIAL TEMPERATURE RANGE  
(0°C – 70°C)

PARAMETER	T <sub>A</sub>	NE531	NE536	N5556 MC1456	N5558 MC1558	LM201	LM301A	LM307	LM308	μA709	μA740	μA741	μA747	μA748	UNITS
Input Offset Voltage (Max)	25°C Over Temp	6 7.5	90	10 14		7.5 10	7.5 10	7.5 10	7.5 10	7.5 10		6 7.5		6 7.5	mV mV
Input Current (Max)	25°C Over Temp	1500 2000	0.1	30 40		1500 2000	250 300	250 300	7 10	1500 2000		500 800		500 800	nA nA
Input Offset Current (Max)	25°C Over Temp	200 300		10 14	DUAL 741	500 750	50 70	50 70	1 1.5	500 750		200 300	DUAL 741	200 300	nA nA
Large Signal Voltage Gain (Min)	25°C	20	25	70		20	25	25	25	15		20		50	V/mV
C.M.R.R. (Min)	25°C	70	64	70		65	70	70	80	65		70		70	dB
P.S.R.R. (Min)	25°C	150	300	200		300	300	300	100	200		150		150	μV/V
Slew Rate A = +1 (Typ)	25°C	30	6	2.5		0.5	0.5	0.5	0.2	0.5	6	0.5		0.5	V/μS
Power Dissipation (Max)	25°C	300	240	90		90	90	90	24	200	240	85		85	mW
Compensation		No	Yes	Yes	Yes	No	No	Yes	No	No	Yes	Yes	Yes	No	

MILITARY TEMPERATURE RANGE  
(-55°C – +125°C)

PARAMETER	T <sub>A</sub>	SE531	SU536 Note 1	S5556 MC1556	S5558 MC1458	LM101	LM101A	LM107	LM108	μA709	μA741	μA747	μA748	UNITS
Input Offset Voltage (Max)	25°C Over Temp	5 6	20 30	4 6		5 6	2 3	2 3	2 3	5 6	5 6		5 6	mV mV
Input Current (Max)	25°C Over Temp	500 1500	0.03 3	15 30	DUAL 741	500 1500	75 100	75 100	2 3	500 1500	500 1500		500 1500	nA nA
Input Offset Current (Max)	25°C Over Temp	200 500		2 5		200 500	10 20	10 20	0.2 0.4	200 500	200 500		200 500	nA nA
Large Signal Voltage Gain (Min)	25°C	50	50	100		50	50	50	50	25	50		50	V/mV
C.M.R.R. (Min)	25°C	70	70	80		70	80	80	80	70	70		70	dB
P.S.R.R. (Min)	25°C	150	150	100		300	100	100	100	150	150		150	μV/V
Slew Rate A = +1 (Typ)	25°C	30	6	2.5		0.5	0.5	0.5	0.2	0.5	0.5		0.5	V/μS
Power Dissipation (Max)	25°C	210	165	45		90	90	90	18	165	85		85	mW
Compensation		No	Yes	Yes	Yes	No	No	Yes	No	No	Yes	Yes	No	

Note 1: -55°C – +85°C

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The Signetics NE501 is a direct-coupled broad-band amplifier fabricated within a monolithic silicon substrate by planar and epitaxial techniques. Typical applications include video amplifiers.

Application flexibility is provided by several external pin connections which adjust the amplifier characteristics to individual needs.

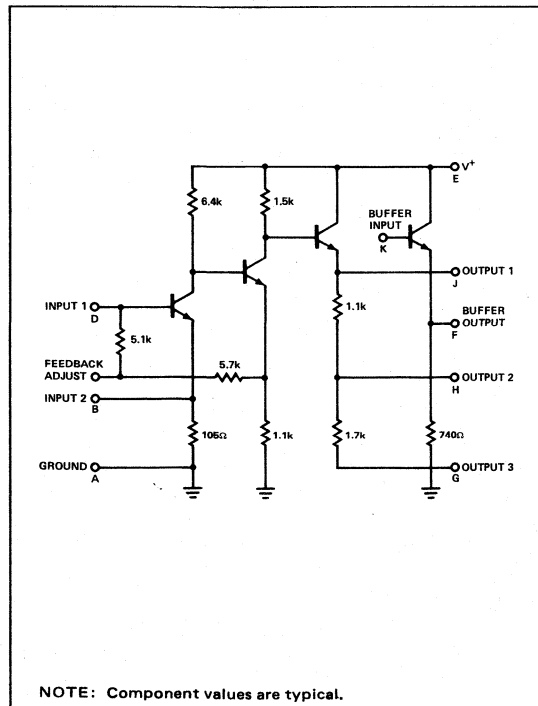
### FEATURES

- ADJUSTABLE GAIN AND IMPEDANCE CHARACTERISTICS
- UNITY GAIN FREQUENCY – 150 MHz
- NOISE FIGURE – 5.0dB
- POWER DISSIPATION – 20mW

### ABSOLUTE MAXIMUM RATINGS

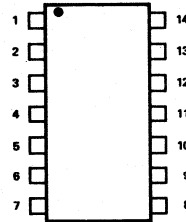
Voltage Applied $V_{G,H,E,C}$	+8.0V
Voltage Applied $V_B$	±3.0V
Voltage Applied $V_{K,D}$	+4.0V
Current Rating $I_{F,J}$	±30mA
Storage Temperature	-65°C to +150°C
Operating Temperature	NE501 0°C to +70°C
	SE501 -55°C to +125°C

### CIRCUIT SCHEMATIC



### PIN CONFIGURATIONS (Top View)

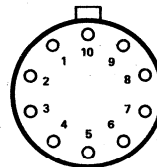
#### A PACKAGE



1. Feedback adjust
2. Input 1
3. NC
4. NC
5. Output 3
6. Input 2
7. Ground
8. Output 2
9.  $V^+$
10. NC
11. NC
12. Buffer output
13. Buffer input
14. Output 1

ORDER PART NOS. SE501A/NE501A

#### K PACKAGE



1. Ground
2. Output 3
3. Input 2
4. Output 2
5.  $V^+$
6. Buffer output
7. Buffer input
8. Output 1
9. Feedback adjust
10. Input 1

ORDER PART NOS. SE501K/NE501K

**SIGNETICS VIDEO AMPLIFIER ■ 501**

**ELECTRICAL CHARACTERISTICS**

PARAMETER	TEST CONDITIONS	NE501			SE501			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Voltage Gain	f = 50 kHz; Notes 1, 2, 6	22.5	24	26.5	23	24	26	dB
Bandwidth (-3dB)	Notes 1, 2, 6	11			14			MHz
Unity Gain Frequency	$A_{V0} = 0\text{dB}$ ; Notes 2, 6	100	150		100	150		MHz
Voltage Gain Stability	f = 50 kHz; T = 0°C; Notes 2, 6	-1.0						dB
	f = 50 kHz; T = +70°C; Notes 2, 6			+0.6				dB
	f = 50 kHz; T = -55°C; Notes 2, 6				-1.0			dB
	f = 50 kHz; T = +125°C; Notes 2, 6						+0.6	dB
Output Voltage	Notes 1, 2, 6, 9	0.71	1.0		0.71	1.0		V <sub>RMS</sub>
Input Impedance	Notes 1, 6; f = 50 kHz; $V_J = V_K$	470		1200	540		1100	Ω
Output Impedance	Notes 1, 2; f = 50 kHz; $V_D = \text{AC ground}$		12	18		12	18	Ω
Output Impedance	Notes 1, 5; f = 50 kHz; $V_D = \text{AC ground}$		25	65		25	50	Ω
Power Dissipation				24			21	mW
Power Dissipation	$V_K = V_J$			60			53	mW
Pulse Response								
Delay Time	Notes 2, 6, 7			15			15	ns
Rise Time	Notes 2, 6, 7		12	20		12	16	ns
Noise Figure	f = 100 kHz; BW = 100 Hz; $Z_s = 500\Omega$ f <sub>c</sub> = 100 kHz; BW = 100 Hz; $Z_s = 500\Omega$ , $V_J = V_K$		5.0	8.0		5.0	7.0	dB

(Notes: 3, 4, 5, 8) Standard Conditions:  $V_E = +6.0\text{V}$ ,  $V_A = 0\text{V}$ ,  $V_G = V_B$ , T = +25°C (except as noted)

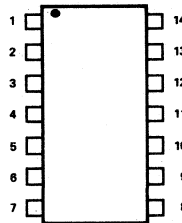
**NOTES:**

- Variations in this parameter depend on optional alternate connections as indicated in accompanying curves.
- Measured at Pin F, with Pins J and K connected.
- Pins not specifically referenced are left electrically open. All voltages are referenced to Pin A. Letter subscripts denote pins on circuit schematic.
- Positive current flow is defined as into the terminal referenced.
- Measured at Pin J.
- Load Resistance = 600Ω, capacitively coupled.
- Delay time is defined as the time interval between the 50% points of  $e_D$  and  $e_F$ . Rise time = 20% to 80% points of  $e_F$ . Input Pulse Characteristics: Amplitude = 25mV; PW = 100ns.
- See Signetics SURE Program Bulletin No. 5001 for definition of Acceptance test Sub-Groups. Sub-Group A-7 is used for the electrical end points for Linear Products.
- Total harmonic distortion less than 5% at  $e_o = 0.71 V_{RMS}$ .

## LINEAR INTEGRATED CIRCUITS

### PIN CONFIGURATIONS (Top View)

#### A PACKAGE



1. Output B
2. Output A
3. Input A
4. Input B
5. Reference
6. Source 1
7. Ground
8. Source 2
9. Bias
10. Input D
11. Input C
12. Output C
13. Output D
14.  $V^+$

ORDER PART NOS. SE510A/NE510A

### DESCRIPTION

The 510 is a dual high-frequency differential amplifier with associated constant current sources and biasing elements contained within a silicon monolithic epitaxial substrate. The large number of accessible internal points provide extreme flexibility of application. The 510 is intended for RF-IF amplifier service to beyond 100 MHz. Circuit layout provides for connection as either a high-gain, common-emitter, common-base, cascode amplifier or a common-collector, common-base, differential amplifier that is useful in critical limiter applications. Automatic gain control may be applied to either circuit.

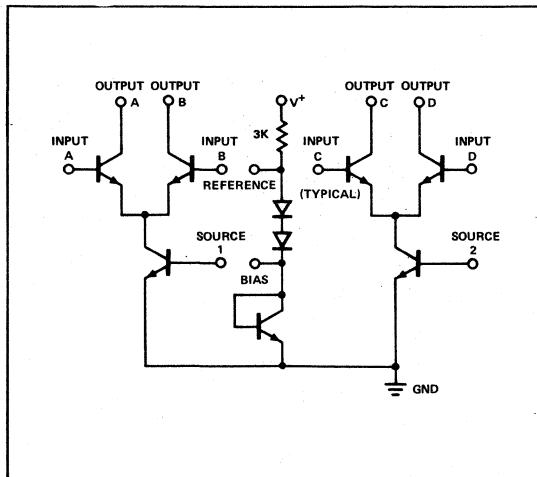
The SE510A meets or exceeds the mechanical and environmental requirements of MIL-S-19500 over the temperature range of  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ .

The NE510A is intended for industrial applications over the temperature range of  $0^{\circ}\text{C}$  to  $+75^{\circ}\text{C}$ .

### FEATURES

- LOW INPUT OFFSET VOLTAGE =  $\pm 2\text{mV}$
- LOW INPUT OFFSET CURRENT =  $\pm 3\mu\text{A}$
- SINGLE POWER SUPPLY
- AGC CAPABILITY
- HIGH FORWARD TRANSADMITTANCE
- LOW FEEDBACK CAPACITANCE

### BASIC CIRCUIT SCHEMATIC



### ABSOLUTE MAXIMUM RATINGS

Applied Voltage ( $V^+$ )	20V
Differential Input Voltage	$\pm 5\text{V}$
Current (All Pins)	$\pm 15\text{mA}$
Storage Temperature	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Operating Temperature	
SE510A	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
NE510A	$0^{\circ}\text{C}$ to $+75^{\circ}\text{C}$

Maximum ratings are limiting values above which serviceability may be impaired.

**SIGNETICS DUAL DIFFERENTIAL AMPLIFIER ■ 510**

**ELECTRICAL CHARACTERISTICS**

PARAMETERS	TEMPERATURE	TEST CONDITIONS	LIMITS						UNITS	
			NE510			SE510				
			MIN	TYP	MAX	MIN	TYP	MAX		
Input Offset Voltage	+25°C 0°C to +70°C -55°C to +125°C	$V_{in} = 0$		0.5 1.0	3 4		0.5 1.5 3.5	2	mV	
Input Offset Current	+25°C 0°C to +70°C -55°C to +125°C			2.0 2.5	6 9		2.0 2.5 7.5	3.5	μA	
Input Bias Current	+25°C 0°C to +70°C -55°C to +125°C			8.0 10.0	25 40		8.0 16.0 40	20	μA	
Differential Collector Current per Differential Pair	+25°C 0°C to +70°C -55°C to +125°C			45 50	75 100		45 50 100	62.5	μA	
Differential Current in the Current Sources	+25°C 0°C to +70°C -55°C to +125°C			30 35	75 100		30 35 100	62.5	μA	
Total Current	+25°C				11.0	15.0		11.0	15.0	mA
Common Mode Rejection Ratio	+25°C			60	80		60	80	dB	

**ELECTRICAL CHARACTERISTICS ( $V^+ = +12V$ ,  $T = 25^\circ C$  applicable from DC to 10 MHz, unless otherwise noted)**

PARAMETER	EMITTER COUPLED CONFIGURATION	CASCADE CONFIGURATION $V_{AGC} = 0V$	UNITS
Input Conductance [ $R_e(Y_{11})$ ]	0.7	3.0	mmho
Output Conductance [ $R_e(Y_{22})$ ]	0.01	0.01	mmho
Input Capacitance	4.5	10	pF
Output Capacitance	2.5	2.5	pF
Reverse Transfer Capacitance	0.05	0.05	pF
Forward Transconductance	25	90	mmho

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 511 is a monolithic dual high frequency differential amplifier with associated constant current source transistors and biasing diode. It is useful from DC to 100 MHz. The circuit arrangement provides for connection as two completely independent emitter coupled (differential) or cascode amplifiers. The bias diode allows stabilization of the current source currents over a large temperature range.

### FEATURES

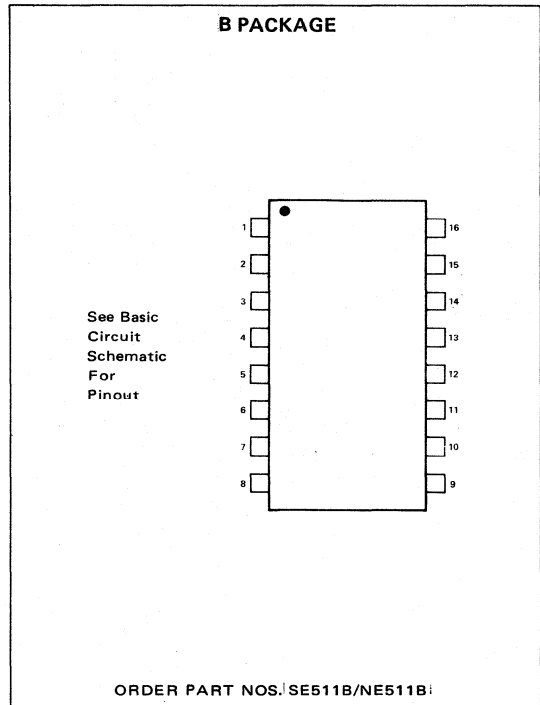
- LOW INPUT OFFSET VOLTAGE =  $\pm 2\text{mV}$
- LOW INPUT OFFSET CURRENT =  $\pm 3\mu\text{A}$
- AGC CAPABILITY
- HIGH FORWARD TRANSADMITTANCE
- LOW FEEDBACK CAPACITANCE
- SINGLE POWER SUPPLY

### ABSOLUTE MAXIMUM RATINGS

Applied Voltage (V+)	20V
Differential Input Voltage	$\pm 5\text{V}$
Current (All Pins)	$\pm 15\text{mA}$
Storage Temperature	$-65^\circ\text{C}$ to $+150^\circ\text{C}$
Operating Temperature	
SE511B	$-55^\circ\text{C}$ to $+125^\circ\text{C}$
NE511B	$0^\circ\text{C}$ to $+75^\circ\text{C}$

Maximum ratings are limiting values above which serviceability may be impaired.

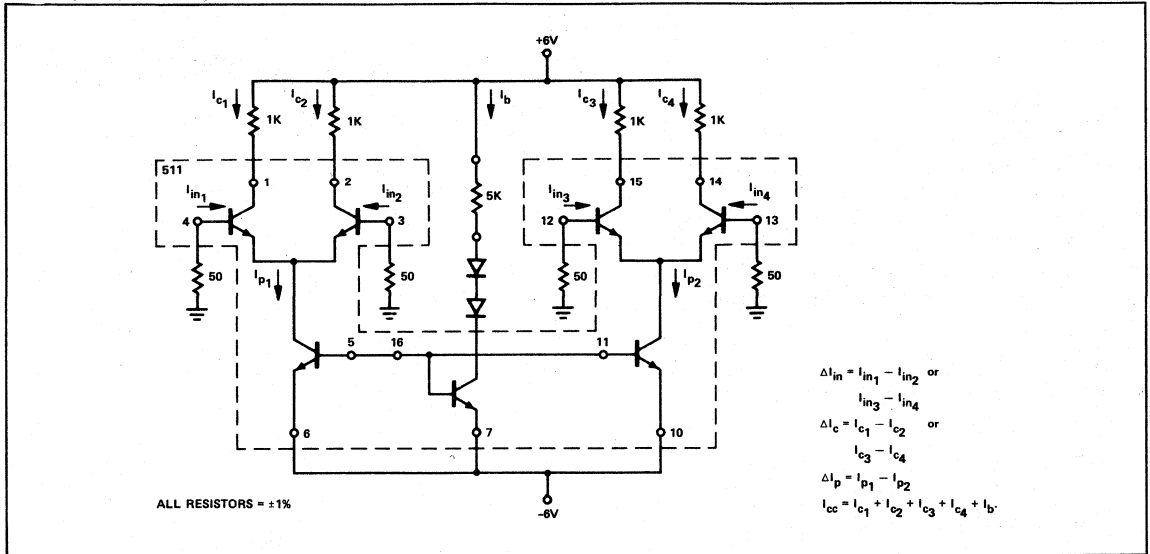
### PIN CONFIGURATIONS (Top View)



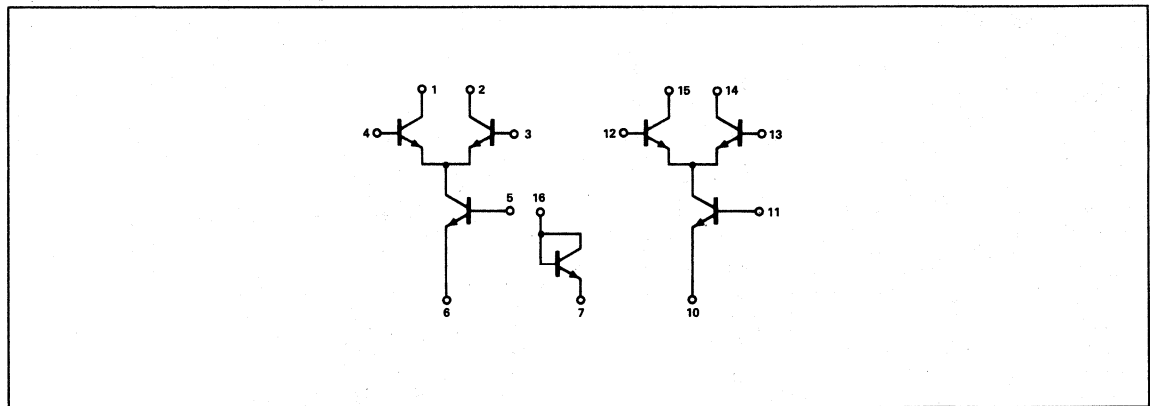
### ELECTRICAL CHARACTERISTICS (Standard Test Circuit)

ACCEPTANCE TEST SUBGROUP	PARAMETERS	SYMBOL	LIMITS						UNITS	TEMPERATURE	TEST CONDITIONS
			MIN		TYP		MAX				
			SE511	NE511	SE511	NE511	SE511	NE511			
A-3	Input Offset Voltage	$\Delta V_{in}$			0.5	0.5	2	3	mV	$+25^\circ\text{C}$	$V_{in} = 0;$ $I_p = 2\text{mA}$
A-4		$\Delta V_{in}$				1.0	4.0		$0^\circ\text{C}$ to $+75^\circ\text{C}$		
A-5		$\Delta V_{in}$			1.5	1.0	3.5	4.0	$-55^\circ\text{C}$ to $+125^\circ\text{C}$		
A-3	Input Offset Current	$\Delta I_{in}$			2.0	2.0	3.5	6	$\mu\text{A}$	$+25^\circ\text{C}$	
A-4		$\Delta I_{in}$				2.5	9		$0^\circ\text{C}$ to $+75^\circ\text{C}$		
A-5		$\Delta I_{in}$			2.5	2.5	7.5		$-55^\circ\text{C}$ to $+125^\circ\text{C}$		
A-3	Input Bias Current	$I_{in}$			8.0	8.0	20	25	$\mu\text{A}$	$+25^\circ\text{C}$	
A-4		$I_{in}$				10.0	40	40	$0^\circ\text{C}$ to $+75^\circ\text{C}$		
A-5		$I_{in}$			16.0	16.0	40		$-55^\circ\text{C}$ to $+125^\circ\text{C}$		
A-3	Differential Collector Current per differential pair	$\Delta I_c$			45	45	62.5	75	$\mu\text{A}$	$+25^\circ\text{C}$	
A-4		$\Delta I_c$				50	100	100	$0^\circ\text{C}$ to $+75^\circ\text{C}$		
A-5		$\Delta I_c$			50	50	100		$-55^\circ\text{C}$ to $+125^\circ\text{C}$		
A-3	Differential Current in the Current Sources	$\Delta I_p$			30	30	62.5	75	$\mu\text{A}$	$+25^\circ\text{C}$	
A-4		$\Delta I_p$				35	100	100	$0^\circ\text{C}$ to $+75^\circ\text{C}$		
A-5		$\Delta I_p$			35	35	100		$-55^\circ\text{C}$ to $+125^\circ\text{C}$		
A-2	Total Current	$I_{cc}$			11.0	11.0	15.0	15.0	mA	$+25^\circ\text{C}$	
A-3	Common Mode Rejection Ratio	CMRR	60	60	80	80			dB	$+25^\circ\text{C}$	
A-3	Output Conductance	$G_{22}$			0.01	0.01			mmho	$+25^\circ\text{C}$	
C-2	Output Capacitance	$C_{ob}$			2.5	2.5			pF	$+25^\circ\text{C}$	
C-2	Input Capacitance	$C_{ib}$			10	10			pF	$+25^\circ\text{C}$	

STANDARD TEST CIRCUIT



BASIC CIRCUIT SCHEMATIC





## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 515 is a general purpose high-gain amplifier with differential input and output. It is fabricated within a monolithic silicon substrate by planar and epitaxial techniques. A pair of compensation points is provided to allow frequency compensation for stable closed loop operation.

This device is not internally referenced to ground and with proper input bias may be operated from a single power supply.

### FEATURES

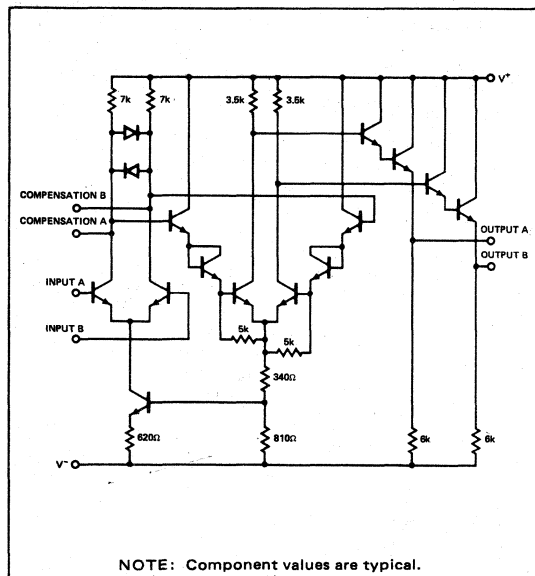
- DIFFERENTIAL VOLTAGE GAIN (Open Loop) = 4,500
- INPUT OFFSET VOLTAGE = 0.5mV
- INPUT OFFSET VOLTAGE STABILITY =  $5.0\mu\text{V}/^\circ\text{C}$
- INPUT COMMON MODE RANGE = +1.5V, -1.0V
- COMMON MODE REJECTION RATIO = 100dB
- BANDWIDTH (Open Loop) = 1.0 MHz

### ABSOLUTE MAXIMUM RATINGS

Applied Voltage (V+ to V-)	12V
Differential Input Voltage (V <sub>5</sub> to V <sub>7</sub> )	±5.0V
Input Current (I <sub>5</sub> , I <sub>7</sub> )	±2.0mA
Output Current (I <sub>2</sub> , I <sub>10</sub> )	±30mA
Storage Temperature	-65°C to +150°C
Operating Temperature	0°C to +75°C
Junction Temperature	150°C

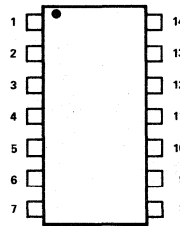
Maximum ratings are limiting values above which serviceability may be impaired.

### EQUIVALENT CIRCUIT



### PIN CONFIGURATIONS (Top View)

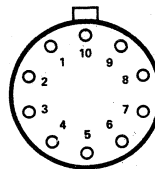
#### A PACKAGE



1. Input B
2. NC
3. NC
4. Compensation
5. NC
6. Output B
7. V<sup>-</sup>
8. Output A
9. NC
10. NC
11. Compensation
12. NC
13. Input A
14. V<sup>+</sup>

ORDER PART NO. NE515A

#### K PACKAGE



1. V<sup>-</sup>
2. Output A
3. NC
4. Compensation
5. Input A
6. V<sup>+</sup>
7. Input B
8. Compensation
9. NC
10. Output B

ORDER PART NOS. SE515K/NE515K

# SIGNETICS DIFFERENTIAL AMPLIFIER ■ 515

## SE515 ELECTRICAL CHARACTERISTICS (Standard Conditions: $V_7 = 0V$ , $V_1 = -3.0V$ ; Notes: 4, 5, 6, 7, 8, 9)

CHARACTERISTIC	$V_6 = +4.0V$	$V_6 = +6.0V$		UNITS	TEMP	TEST CONDITIONS	
	TYP	MIN	TYP				MAX
Open Loop Voltage Gain (dc)	2,500	3,500	4,500		V/V	+25°C	Note 2
	1,800		3,000		V/V	+125°C	
Open Loop Voltage Gain (ac)	2,000	2,500	3,500		V/V	+25°C	f = 800 kHz
Input Offset Voltage	0.5		0.5	3.0	mV	-55°C	Note 1
	0.5		0.5	2.0	mV	+25°C	
	0.5		0.5	3.0	mV	+125°C	
Input Bias Current	18		25	40	$\mu A$	-55°C	Note 1
	12		16	24	$\mu A$		
Differential Input Resistance	2.0	1.0	1.5		k $\Omega$	-55°C	Note 10
	4.0	2.0	3.2		k $\Omega$	+25°C	
Input Common Mode Range	$\pm 1.0$		+1.5		V	+25°C	
			-1.0				
Balanced Output dc Level	-0.1		+1.2	+1.8	V	-55°C	Note 1
	+0.3		+1.6		V	+25°C	
	+0.6		+1.9		V	+125°C	
Output Voltage Swing	4.7	5.7	6.3		V	-55°C	Note 3
	4.7	5.7	6.3		V	+25°C	
	4.7	5.7	6.3		V	+125°C	
					V		
High Output Level	+2.3	+4.0	+4.3		V	-55°C	$V_5 = 10mV$
	+2.6	+4.3	+4.6		V	+25°C	
	+3.0	+4.7	+5.0		V	+125°C	
Low Output Level	-2.4	-1.7	-2.0		V	-55°C	$V_5 = 10mV$
	-2.1	-1.4	-1.7		V	+25°C	
	-1.7	-1.0	-1.3		V	+125°C	
Output Resistance	100		100		$\Omega$	+25°C	Note 1
Common Mode Rejection Ratio	100		100		dB		
Power Supply Current				7.0	mA		Note 1
				7.0	mA		
	3.5		5.5	7.0	mA		

### NOTES:

- Adjust  $V_5$  to obtain  $V_2 = V_{10}$ .
- Output voltage swing = 1.3V peak to peak.
- Output voltage swing is guaranteed by output voltage limit tests.
- Voltage and current subscripts refer to pin numbers.
- All measurements are referenced to power supply common. Positive current flow is defined as into the terminal indicated.
- All specifications herein apply for interchange of voltages and currents at Pins 5 and 7.
- Acceptance Test Sub-Group references apply to minimum and maximum limits only.
- The SE515K has Pins 1, 3 and 9 connected to the case. The SE515Q has Pins 3 and 9 open.
- See Signetics SURE Program Bulletin No. 5001 for definition of Acceptance Test Sub-Groups. Sub-Group A-7 is used for electrical end points for Linear Products.
- Differential Input Resistance is computed from input bias current.

NE515 ELECTRICAL CHARACTERISTICS (Standard Conditions:  $V_B = 0V$ ,  $V_A = 3.0V$ ; Notes: 4, 5, 6, 7, 8, 9)

CHARACTERISTIC	$V_F = +4.0V$	$V_F = +6.0V$			UNITS	TEMP	TEST CONDITIONS
	TYP	MIN	TYP	MAX			
Open Loop Voltage Gain (dc)	1,800	2,500	3,200		V/V	+25°C	Note 2
	1,350		2,200		V/V	+75°C	
Open Loop Voltage Gain (ac)	1,500	1,700	2,500		V/V	+25°C	f = 800 kHz
Input Offset Voltage	0.5		0.5	4.0	mV	0°C	Note 1
	0.5		0.5	3.0	mV	+25°C	
	0.5		0.5	4.0	mV	+75°C	
Input Bias Current	18		25	40	μA	0°C	Note 1
	15		20	31	μA	+25°C	
Differential Input Resistance	3.2	1.4	2.3		kΩ	0°C	Note 10
	3.5	1.7	2.6		kΩ	+25°C	
Input Common Mode Range	±1.0		+1.5		V	+25°C	
			-1.0				
Balanced Output dc Level	-0.1		+1.2		V	0°C	Note 1
	+0.3		+1.6	+1.8	V	+25°C	
	+0.6		+1.9		V	+75°C	
Output Voltage Swing	4.5	5.3	6.1		V	0°C	Note 3
	4.5	5.3	6.1		V	+25°C	
	4.5	5.3	6.1		V	+75°C	
High Output Level	+2.3	+3.9	+4.3		V	0°C	$V_C = 10mV$
	+2.5	+4.1	+4.5		V	+25°C	
	+2.8	+4.3	+4.8		V	+75°C	
Low Output Level	-2.2	-1.4	-1.8		V	0°C	$V_C = 10mV$
	-2.0	-1.2	-1.6		V	+25°C	
	-1.7	-1.0	-1.3		V	+75°C	
Output Resistance	100		100		Ω	+25°C	Note 1
Common Mode Rejection Ratio	100		100		dB	+25°C	
Power Supply Current				7.0	mA	0°C	Note 1
	3.5		5.5	7.0	mA	+25°C	
				7.0	mA	+75°C	

Letter subscripts refer to pins on circuit schematic.

NOTES:

- Adjust  $V_C$  to obtain  $V_G = V_H$ .
- Output voltage swing = 1.3V peak to peak.
- Output voltage swing is guaranteed by output voltage limit tests.
- Voltage and current subscripts refer to pin numbers.
- All measurements are referenced by power supply common. Positive current flow is defined as into the terminal indicated.
- All specifications herein apply for interchange of voltages and currents at Pins B and C.
- Acceptance Test Sub-Group references apply to minimum and maximum limits only.
- The NE515K has Pins 1, 3 and 9 connected to the case. The NE515G has Pins 3 and 9 open.
- See Signetics SURE Program Bulletin No. 5001 for definition of Acceptance Test Sub-Groups. Sub-Group A-7 is used for electrical end points for Linear Products.
- Differential Input Resistance is computed from input bias current.

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE521 is an ultra high speed dual voltage comparator which features less than 12ns propagation delay without sacrificing input performance characteristics. The NE521 comparator maintains  $\pm 3V$  minimum common mode voltage range, 7.5mV input offset voltage and 5 $\mu A$  offset current. The NE521 utilizes Schottky technology at critical points in the circuit in order to minimize delay.

The NE521 features TTL compatible output levels with a minimum sink/source capability of 10 Schottky gate loads.

### FEATURES

- 12 ns MAXIMUM GUARANTEED PROPAGATION DELAY
- 20  $\mu A$  MAXIMUM INPUT BIAS CURRENT
- TTL COMPATIBLE STROBES AND OUTPUTS
- LARGE COMMON MODE INPUT VOLTAGE RANGE
- OPERATES FROM STANDARD SUPPLY VOLTAGES

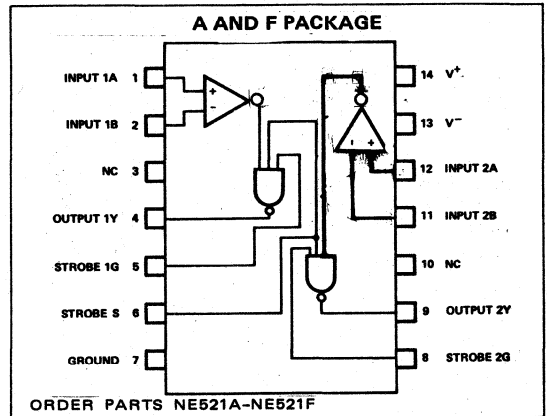
### APPLICATIONS

- MOS MEMORY SENSE AMP
- A/D CONVERSION
- HIGH SPEED LINE RECEIVER

### ABSOLUTE MAXIMUM RATINGS

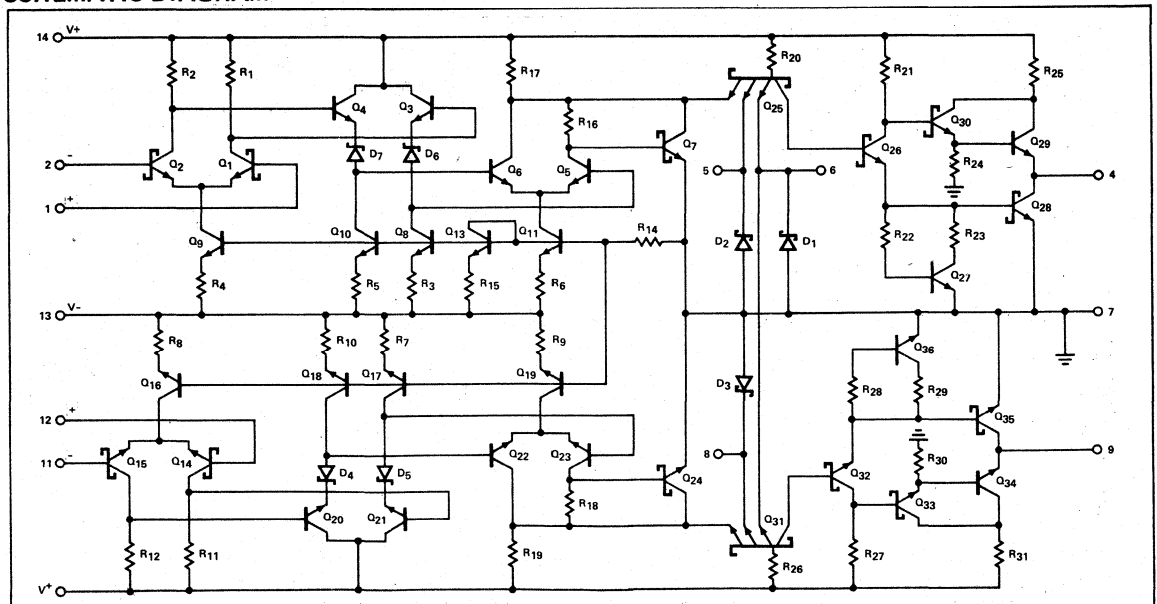
Positive Supply Voltage (V+) +7 Volts  
 Negative Supply Voltage (V-) -7 Volts

### PIN CONFIGURATION (Top View)



Differential input voltage	$\pm 6$ Volts
Common mode input voltage	$\pm 5$ Volts
Strobe/Gate input voltage	+5.25 Volts
Power Dissipation	600 mw
Operating Temperature Range	
NE521	0°C to 70°C
Storage temperature range	-65°C to +150°C
Lead temperature (Soldering 60 seconds)	+300°C

### SCHEMATIC DIAGRAM



ELECTRICAL CHARACTERISTICS  $V_+ = +5.00$ ,  $V_- = -5.00$ ,  $T_A = 0$  to  $70^\circ\text{C}$  (Unless otherwise noted).

PARAMETER	CONDITIONS	NE521			UNITS
		MIN	TYP	MAX	
<b>Amplifier Input</b>					
Input offset voltage @ $25^\circ\text{C}$	$V_+ = 4.75$ , $V_- = -4.75$	—	6	7.5	mV
over temp range	$V_+ = 4.75$ , $V_- = -4.75$			10	mV
Input Bias Current @ $25^\circ\text{C}$	$V_+ = 5.25$ , $V_- = -5.25$	—	7.5	20	$\mu\text{A}$
over temp range	$V_+ = 5.25$ , $V_- = -5.25$	—	—	40	$\mu\text{A}$
Input offset current @ $25^\circ\text{C}$	$V_+ = 5.25$ , $V_- = -5.25$	—	1.0	5	$\mu\text{A}$
over temp range	$V_+ = 5.25$ , $V_- = -5.25$	—	—	12	$\mu\text{A}$
Input common mode voltage range	$V_+ = 4.75$ , $V_- = -4.75$	$\pm 3$			Volts
Input resistance			4		$\text{K}\Omega$
Input capacitance			3	6	pF
Voltage gain			5		V/mV
<b>Schottky Gate/Output Characteristics</b>					
$I_{IH}$ high level input current into 1 G or 2 G strobe	$V_+ = 5.25$ , $V_- = 5.25$ $V_{IH} = 2.7\text{V}$			50	$\mu\text{A}$
$I_{IH}$ High level input current into common strobe S	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IH} = 2.7\text{V}$			100	$\mu\text{A}$
$I_{IL}$ low level input current into 1 G or 2 G	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IL} = 0.5\text{V}$			-2.0	mA
$I_{IL}$ low level input current current into common strobe S	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IL} = 0.5\text{V}$			-4.0	mA
$V_{OH}$ high level output voltage	$V_+ = 4.75\text{V}$ , $V_{I(S)} = 2.0\text{V}$ $V_- = -4.75\text{V}$ 1 load = -1 mA	2.7	3.4		V
$V_{OL}$ low level output voltage	$V_+ = 5.25$ $V_- = 5.25$ 1 load = 20mA			0.5	V
<b>Power Supply Requirements</b>					
Supply Voltage					
$V_+$		4.75	5.00	5.25	Volts
$V_-$		-4.75	-5.00	-5.25	Volts
Supply current	$V_+ = 5.25\text{V}$ $V_- = -5.25\text{V}$ $T_A = 25^\circ\text{C}$				
$I_{CC+}$			27	50	mA
$I_{CC-}$			-15	-28	mA
$I_{OS}$ short circuit Output current	$V_+ = +5.25$ $V_- = -5.25$	-40		-100	mA
<b>Large Signal Switching Speed</b>					
$T_{pLH}$ (D) low to high propagation delay from amp inputs to output	$R_L = 280\Omega$ $C_L = 15\text{pF}$ $T_A = 25^\circ\text{C}$ Note 1		8	12	nsec
$T_{pHL}$ (D) high to low propagation delay from amp inputs to output	$R_L = 280\Omega$ $C_L = 15\text{pF}$ $T_A = 25^\circ\text{C}$ Note 1		6	9	nsec
$T_{pLH}$ (S) low to high propagation delay from strobes input to output	$R_L = 280\Omega$ $C_L = 15\text{pF}$ $T_A = 25^\circ\text{C}$ Note 2		4.5	6	nsec
$T_{pHL}$ (S) high to low propagation delay strobe input to output	$R_L = 280\Omega$ $C_L = 15\text{pF}$ $T_A = 25^\circ\text{C}$ Note 2		3.0	4.5	nsec
Maximum Operating Frequency	$R_L = 280\Omega$ $C_L = 15\text{pF}$ $T_A = 25^\circ\text{C}$	40	55		MHz

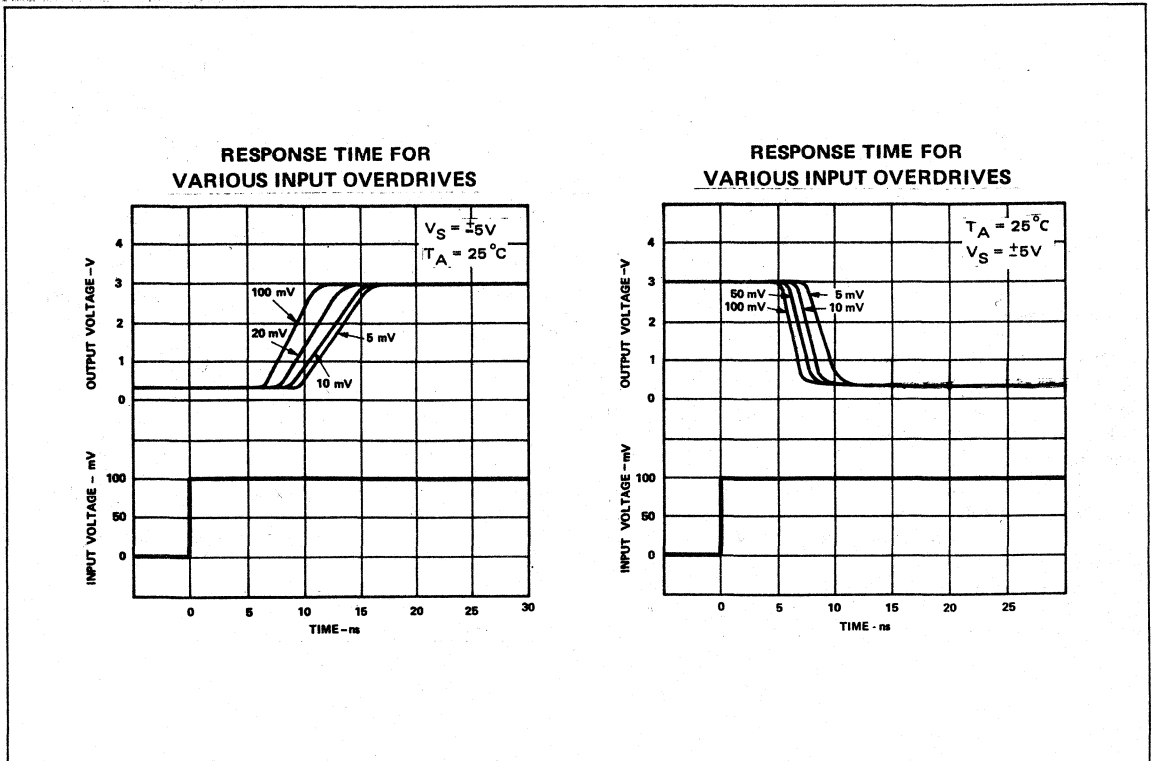
ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER	CONDITIONS				UNITS
		MIN	TYP	MAX	
<b>Small Signal Switching Characteristics (5 mV)</b>					
$T_{pLH}$ (D) low to high propagation delay from amplifier inputs to output	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$ Note 3		12	18	nsec
$T_{pHL}$ (D) high to low propagation delay from amplifier inputs to output	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$ Note 3		10	15	nsec

NOTES:

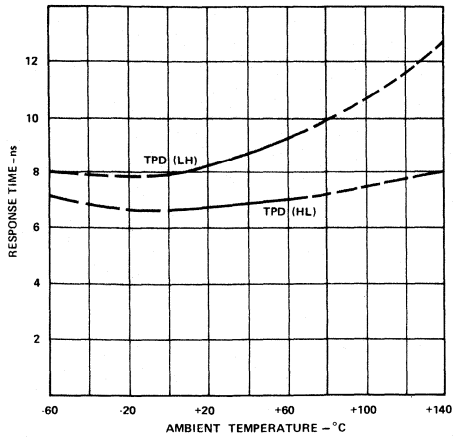
1. Response time measured from 0 volt point of  $\pm 100$  mV p-p 10MHz square wave to the 1.5V point of the output.
2. Response time measured from 1.5V point of input to 1.5V point of the output.
3. Response time measured from the start of a 100mv input step with 5mv over drive to the 1.5V point of the output.

TYPICAL PERFORMANCE CHARACTERISTICS

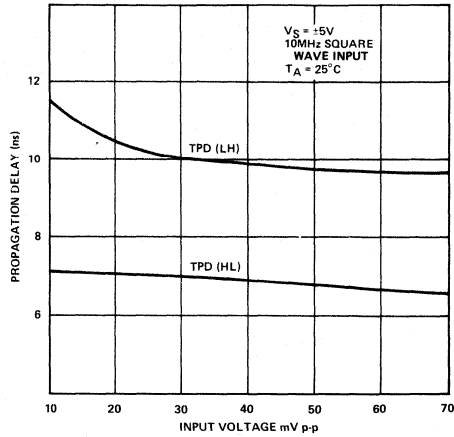


TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)

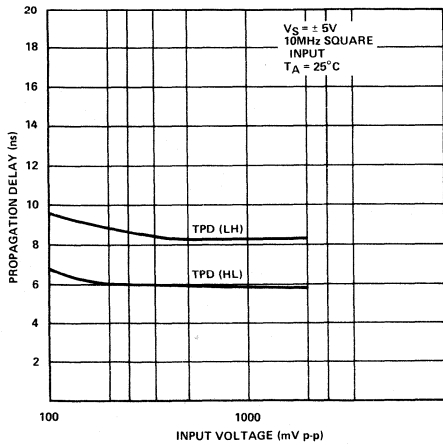
RESPONSE TIME VS. TEMPERATURE



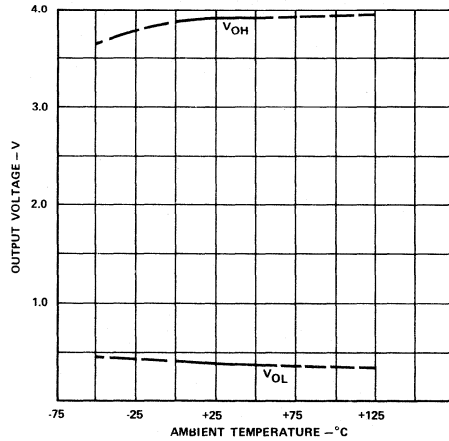
PROPAGATION DELAY FOR VARIOUS INPUT VOLTAGES



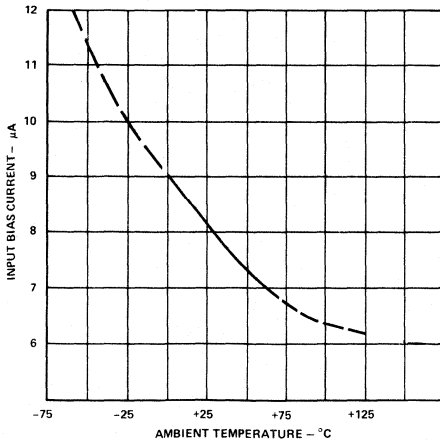
PROPAGATION DELAY FOR VARIOUS INPUT VOLTAGES



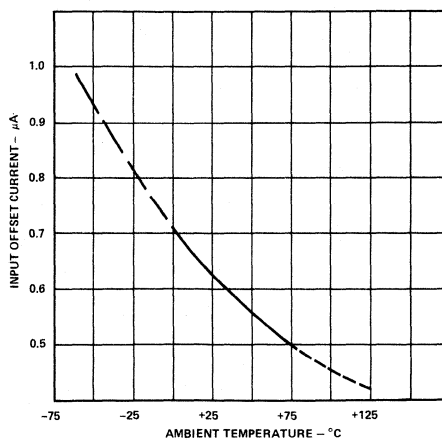
OUTPUT VOLTAGE VS. AMBIENT TEMPERATURE



INPUT BIAS CURRENT VS. AMBIENT TEMPERATURE



INPUT OFFSET CURRENT VS. AMBIENT TEMPERATURE



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE522 is an ultra high speed dual voltage comparator which features less than 15 ns propagation delay without sacrificing input performance characteristics. The NE522 comparator maintains  $\pm 3V$  minimum common mode voltage range, 7.5mV input offset voltage and 5 $\mu A$  offset current. The NE522 utilizes Schottky technology at critical points in the circuit in order to minimize delay.

The NE522 features open collector output structures for "wire-or'd" applications.

### FEATURES

- 15 ns MAXIMUM GUARANTEED PROPAGATION DELAY
- 20  $\mu A$  MAXIMUM INPUT BIAS CURRENT
- TTL COMPATIBLE STROBES AND OUTPUTS
- OPEN COLLECTOR OUTPUT FOR "WIRE-OR'D" APPLICATIONS
- LARGE COMMON MODE INPUT VOLTAGE RANGE
- OPERATES FROM STANDARD SUPPLY VOLTAGES

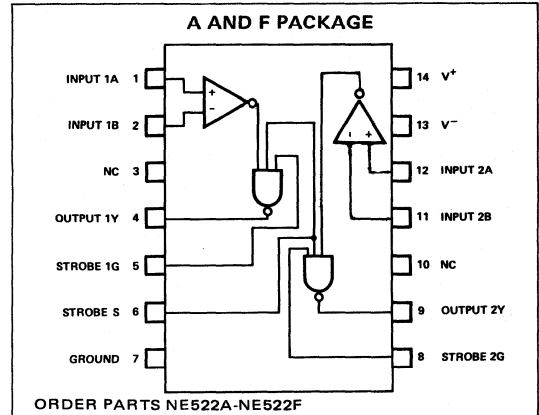
### APPLICATIONS

- MOS MEMORY SENSE AMP
- A/D CONVERSION
- HIGH SPEED LINE RECEIVER

### ABSOLUTE MAXIMUM RATINGS

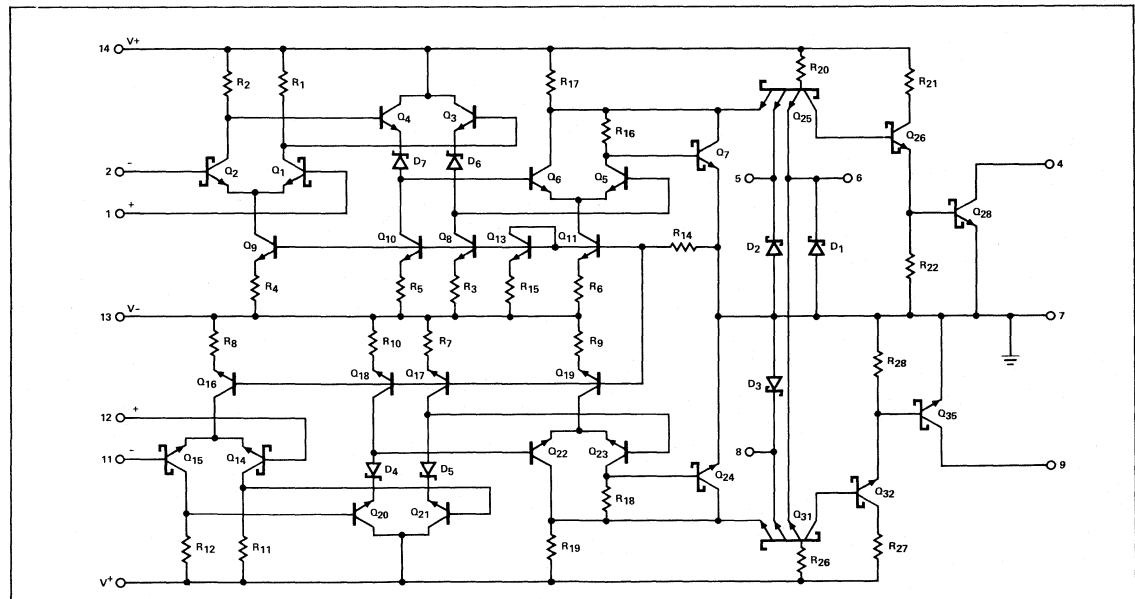
Positive Supply Voltage (V+) +7 Volts

### PIN CONFIGURATION (Top View)



Negative Supply Voltage (V-)	-7 Volts
Differential input voltage	$\pm 6$ Volts
Common mode input voltage	$\pm 5$ Volts
Strobe/Gate input voltage	+5.25 Volts
Power Dissipation	600 mw
Operating Temperature Range	
NE522	0°C to 70°C
Storage temperature range	-65°C to +150°C
Lead temperature (Soldering 60 seconds)	+300°C

### SCHEMATIC DIAGRAM





ELECTRICAL CHARACTERISTICS  $V_+ = +5.00$ ,  $V_- = -5.00$ ,  $T_A = 0$  to  $70^\circ\text{C}$  (Unless otherwise noted)

PARAMETER	CONDITIONS	NE522			UNITS
		MIN	TYP	MAX	
<b>Amplifier Input</b>					
Input offset voltage @ $25^\circ\text{C}$	$V_+ = 4.75$ , $V_- = -4.75$	—	6	7.5	mV
over temp range	$V_+ = 4.75$ , $V_- = -4.75$			10	mV
Input Bias Current @ $25^\circ\text{C}$	$V_+ = 5.25$ , $V_- = -5.25$	—	7.5	20	$\mu\text{A}$
over temp range	$V_+ = 5.25$ , $V_- = -5.25$	—	—	40	$\mu\text{A}$
Input offset current @ $25^\circ\text{C}$	$V_+ = 5.25$ , $V_- = -5.25$	—	1.0	5	$\mu\text{A}$
over temp range	$V_+ = 5.25$ , $V_- = -5.25$	—	—	12	$\mu\text{A}$
Input common mode voltage range	$V_+ = 4.75$ , $V_- = -4.75$	$\pm 3$			Volts
Input resistance			4		$\text{K}\Omega$
Input capacitance			3	6	pF
Voltage gain			5		V/mV
<b>Schottky Gate/Output Characteristics</b>					
$I_{IH}$ high level input current into 1 G or 2 G strobe	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IH} = 2.7\text{V}$			50	$\mu\text{A}$
$I_{IH}$ high level input current into common strobe S	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IH} = 2.7\text{V}$			100	$\mu\text{A}$
$I_{IL}$ low level input current into 1 G or 2 G	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IL} = 0.5\text{V}$			-2.0	mA
$I_{IL}$ low level input current current into common strobe S	$V_+ = 5.25$ , $V_- = -5.25$ $V_{IL} = 0.5\text{V}$			-4.0	mA
$V_{OL}$ low level output voltage	$V_+ = 5.25$ , $V_{I(S)} = 2.0\text{V}$ $V_- = -5.25$			0.5	V
$I_{OH}$ high level output current	1 load = 20mA $V_+ = +4.75\text{V}$ $V_- = -4.75\text{V}$ $V_{OH} = 5.25\text{V}$			250	$\mu\text{A}$
<b>Power Supply Requirements</b>					
Supply Voltage					
$V_+$		4.75	5.00	5.25	Volts
$V_-$		-4.75	-5.00	-5.25	Volts
Supply current	$V_+ = 5.25\text{V}$ $V_- = -5.25\text{V}$ $T_A = 25^\circ\text{C}$				
$I_{CC+}$			27	50	mA
$I_{CC-}$			-15	-28	mA
<b>Large Signal Switching Speed</b>					
$T_{pLH}$ (D) low to high propagation delay from amp inputs to output	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$ Note 1		10	15	nsec
$T_{pHL}$ (D) high to low propagation delay from amp inputs to output	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$ Note 1		8	12	nsec
$T_{pLH}$ (S) low to high propagation delay from strobes input to output	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$ Note 2		6	10	nsec
$T_{pHL}$ (S) high to low propagation delay strobe input to output	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$ Note 2		5	8	nsec
Maximum Operating Frequency	$R_L = 280\Omega$ $C_L = 15$ pF $T_A = 25^\circ\text{C}$	25	35		MHz

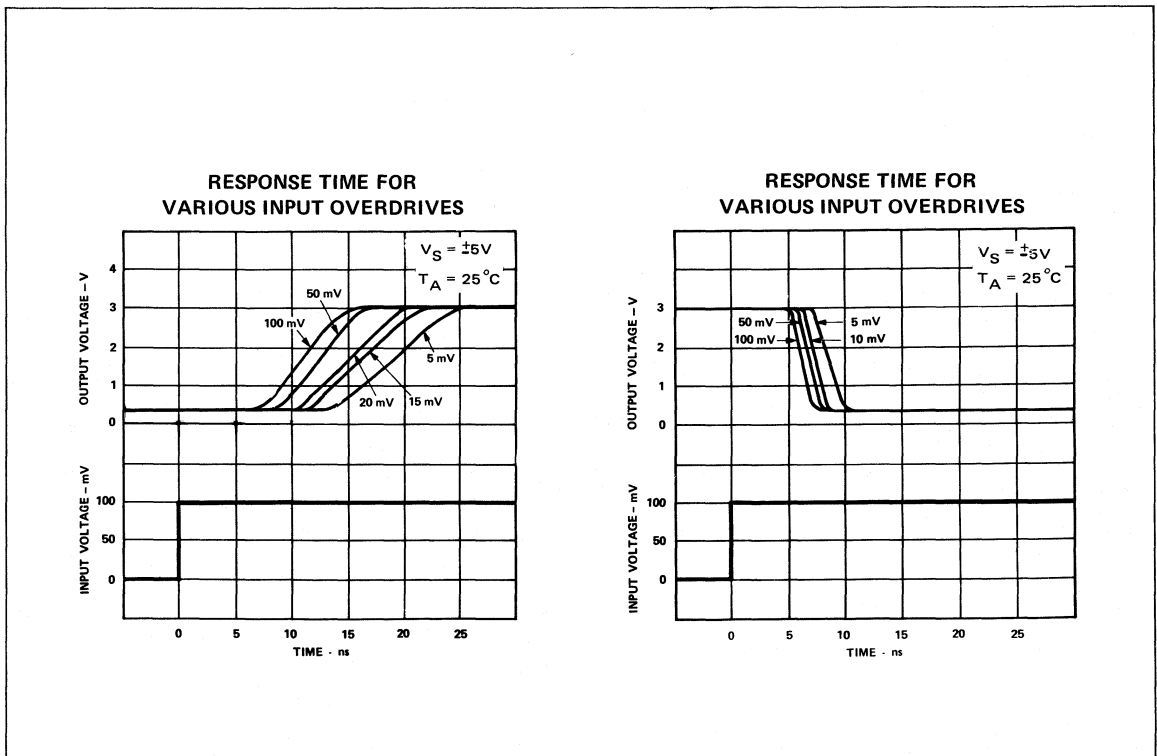
ELECTRICAL CHARACTERISTICS (Cont'd)

PARAMETER	CONDITIONS	NE522			UNITS
		MIN	TYP	MAX	
<b>Small Signal Switching Characteristics (5 mV)</b> T <sub>p</sub> LH (D) low to high propagation delay from amplifier inputs to output T <sub>p</sub> HL (D) high to low propagation delay from amplifier inputs to output	R <sub>L</sub> = 280Ω C <sub>L</sub> = 15 pF T <sub>A</sub> = 25°C Note 3 R <sub>L</sub> = 280Ω C <sub>L</sub> = 15 pF T <sub>A</sub> = 25°C Note 3		17	25	nsec
			11	17	nsec

NOTES:

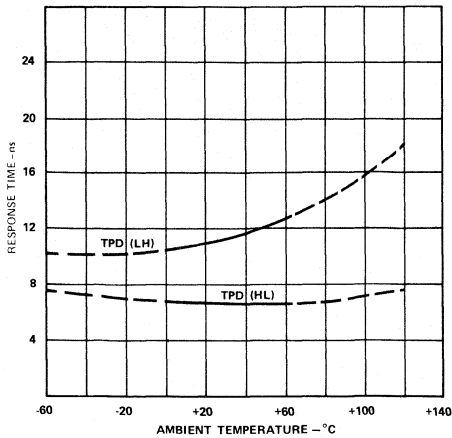
- Response time measured from 0V of ±100 mV p-p 10MHz square wave to the 1.5V point of the output.
- Response time measured from 1.5V point of input to 1.5V point of the output.
- Response time measured from the start of a 100mv input step with 5mv over drive to the 1.5v point of the output.

TYPICAL PERFORMANCE CHARACTERISTICS

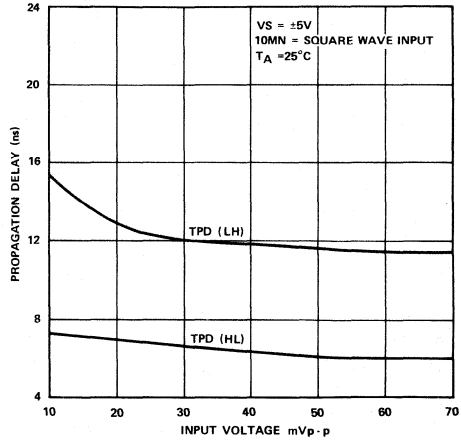


TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)

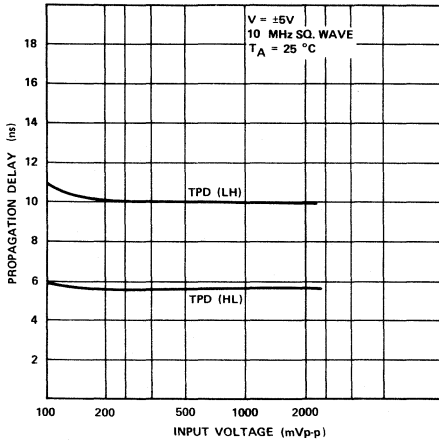
RESPONSE TIME VS. TEMPERATURE



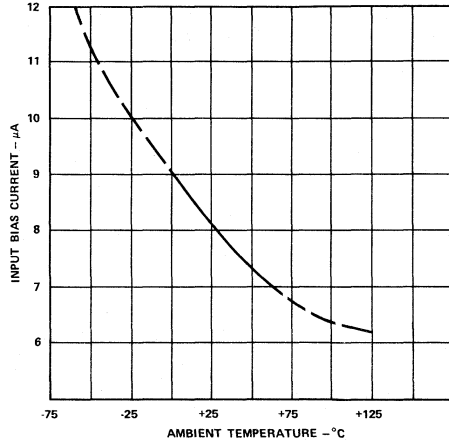
PROPAGATION DELAY FOR VARIOUS INPUT VOLTAGE



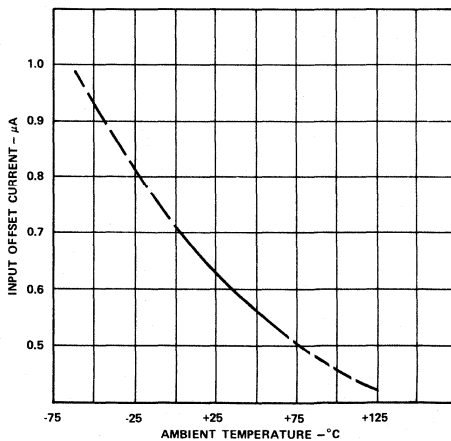
PROPAGATION DELAY FOR VARIOUS INPUT VOLTAGES



INPUT BIAS CURRENT VS. AMBIENT TEMPERATURE



INPUT OFFSET CURRENT VS. AMBIENT TEMPERATURE



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 526 is a high speed analog comparator intended for use in systems where low propagation delay and fast recovery from common mode or differential input overdrive is required. The device is specifically designed to provide a wide input common mode range while operating from power supplies commonly found in digital logic systems.

The 526 consists of a medium gain, high frequency differential amplifier and a high speed TTL gate fabricated within a single substrate by planar and epitaxial techniques. The output gate of the 526 has voltage and current capabilities compatible with DCL, DTL and TTL. The 526 output gate has a full fan-out of 10 to standard TTL loads.

The amplifier and gate may be used independently or cascaded for applications as a voltage comparator, digital line receiver or sense amplifier. The second gate input is used to provide strobe capability when operating the amplifier and gate in cascade.

### FEATURES

- PROPAGATION DELAY 30ns
- INPUT COMMON MODE RANGE +4.5V  
-3.5V
- DIFFERENTIAL OVERDRIVE RECOVERY 20ns
- OUTPUT COMPATIBLE WITH  
STANDARD LOGIC FORMS
- OPERATES FROM STANDARD  $\pm 5V$  SUPPLIES

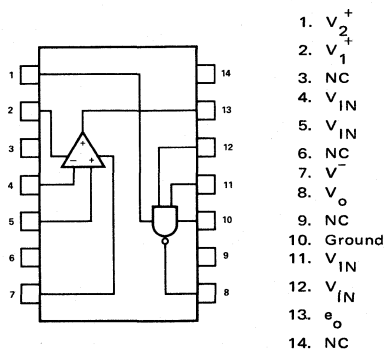
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	+7.0V
Gate Input Voltage	+6.0V
Differential Input Voltage	+5.0V
Common Mode Input Voltage	+5.0V
Gate Output Current	+100 mA
Storage Temperature	-65°C to +150°C
Operating Temperature	SE526 -55°C to +125°C NE526 0°C to +75°C

Absolute Maximum Ratings are limiting values above which serviceability may be impaired.

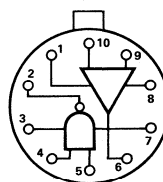
### PIN CONFIGURATION (Top View)

#### A PACKAGE



ORDER PART NOS.  
SE526A/NE526A

#### K PACKAGE



ORDER PART NOS.  
SE526K/NE526K

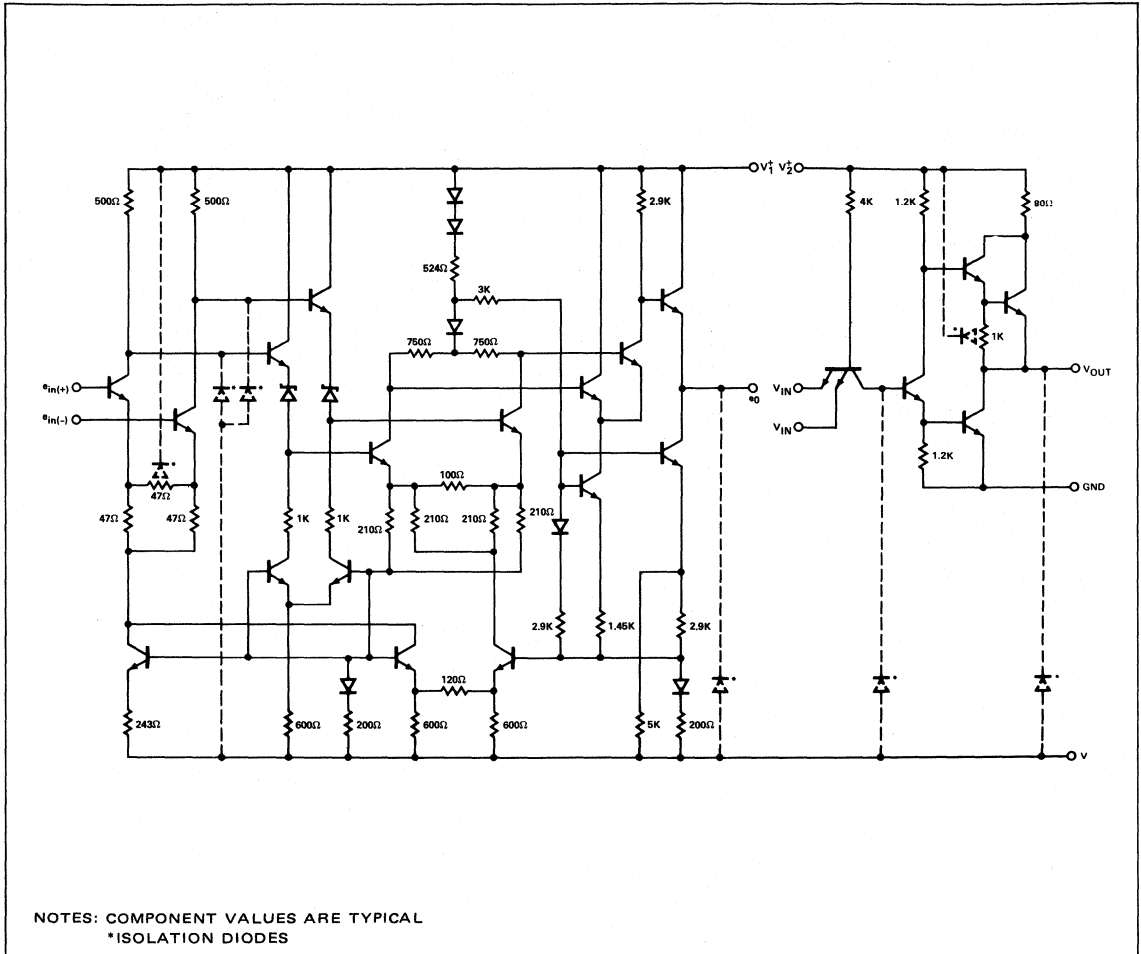
ELECTRICAL CHARACTERISTICS (Standard Conditions:  $V_1^+ = V_2^+ = 5.0V$ ,  $V^- = -5.0V$ ; Notes 1,2,3,4,13,14)

CHARACTERISTIC	SYMBOL	LIMITS				TEMPERATURE		NOTES
		MIN.	TYP.	MAX.	UNIT	SE526	NE526	
Input Offset Voltage	$V_{io}$		2.0	5.0	mV	-55°C	0°C	5
	$V_{io}$		2.0	5.0	mV	+25°C	+25°C	5
	$V_{io}$		2.0	5.0	mV	+125°C	+75°C	5
Input Bias Current	$I_{in}$		30.0	35.0	μA	-55°C	0°C	6
	$I_{in}$		25.0	35.0	μA	+25°C	+25°C	6
	$I_{in}$		22.0	35.0	μA	+125°C	+75°C	6
Input Offset Current	$I_{io}$		0.6	5.0	μA	-55°C	0°C	
	$I_{io}$		0.5	5.0	μA	+25°C	+25°C	
	$I_{io}$		0.4	5.0	μA	+125°C	+75°C	
Input Common Mode Range	$V_{cm}$	+4.2	+4.7		V	-55°C	0°C	
	$V_{cm}$	+4.2	+4.5		V	+25°C	+25°C	
	$V_{cm}$	+4.2	+4.4		V	+125°C	+75°C	
	$V_{cm}$	-3.2	-3.5		V	-55°C	0°C	
	$V_{cm}$	-3.2	-3.5		V	+25°C	+25°C	
	$V_{cm}$	-3.2	-3.5		V	+125°C	+75°C	
Amplifier Output Voltage	$V_{ohi}$	3.5			V	-55°C	0°C	
	$V_{ohi}$	3.5			V	+25°C	+25°C	
	$V_{ohi}$	3.5			V	+125°C	+75°C	
	$V_{olo}$			0.6	V	-55°C	0°C	
	$V_{olo}$			0.5	V	+25°C	+25°C	
	$V_{olo}$			0.4	V	+125°C	+75°C	
Amplifier Power Consumption	$P_d$		90	120	m/W	-55°C	0°C	
	$P_d$		100	120	m/W	+25°C	+25°C	
	$P_d$		110	120	m/W	+125°C	+75°C	
Gate Output Voltage	$V_{1o}$	2.8	3.5		V	-55°C	0°C	7, 8
	$V_{1o}$	2.8	3.2		V	+25°C	+25°C	7, 8
	$V_{1o}$	2.8	3.0		V	+125°C	+75°C	7, 8
	$V_{0o}$		0.3	0.4	V	-55°C	0°C	7, 8
	$V_{0o}$		0.2	0.4	V	+25°C	+25°C	7, 8
	$V_{0o}$		0.3	0.4	V	+125°C	+75°C	7, 8
Gate Output Sink Current	$I_{0o}$	16.0			mA	+25°C	+25°C	8
Gate Output Source Current	$I_{1o}$	1.0			mA	+25°C	+25°C	7
Gate Input Threshold Voltage	$V_{1i}$	2.0			V	-55°C	0°C	9
	$V_{1i}$	2.0			V	+25°C	+25°C	9
	$V_{1i}$	2.0			V	+125°C	+75°C	9
	$V_{0i}$			1.0	V	-55°C	0°C	10
	$V_{0i}$			0.9	V	+25°C	+25°C	10
	$V_{0i}$			0.8	V	+125°C	+75°C	10
Gate Input Current (Input "0")	$I_{0i}$	-0.1	-1.2	-1.6	mA	-55°C	0°C	
	$I_{0i}$	-0.1	-1.4	-1.6	mA	+25°C	+25°C	
	$I_{0i}$	-0.1	-1.2	-1.6	mA	+125°C	+75°C	
	$I_{1i}$		5	25	μA	-55°C	0°C	
	$I_{1i}$		10	25	μA	+25°C	+25°C	
	$I_{1i}$		15	25	μA	+125°C	+75°C	
Gate Current Consumption (Output "1")	$I_{CC1}$			2.00	mA	-55°C	0°C	
	$I_{CC1}$			2.00	mA	+25°C	+25°C	
	$I_{CC1}$			2.00	mA	+125°C	+75°C	
	$I_{CC0}$			5.00	mA	-55°C	0°C	
	$I_{CC0}$			5.00	mA	+25°C	+25°C	
	$I_{CC0}$			5.00	mA	+125°C	+75°C	
Gate Input Latch Voltage Rating	$BV_i$			6.0	V	+25°C	+25°C	
Gate Output Short Circuit Current	$I_{so}$	-10.0		-70.0	mA	+25°C	+25°C	
Switching Times	$T_{on}$		15	17	ns	+25°C	+25°C	11
	$T_{off}$		15	17	ns	+25°C	+25°C	11
	$T_{pd0}$		30	42	ns	+25°C	+25°C	11
	$T_{pd1}$		40	48	ns	+25°C	+25°C	11
	Differential Overload Recovery	$t_{dm}$		30	40	ns	+25°C	+25°C

Recommended Operating Supply Voltages ( $V_1^+ = V_2^+ = 5.0V$ ,  $V^- = -5.0V$ )

- NOTES:**
- All measurements are referenced to the ground terminal.
  - Positive current is defined as into the pin referenced.
  - Pins not specifically referenced are left electrically open.
  - Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
  - Input Offset Voltage is tested at guaranteed Input Common Mode Range voltage limits and includes the worst-case variations of voltage gain and input impedance. These are the maximum values required to drive the output down to "0" or up to "1".
  - Input Bias Current is defined as the maximum current required to bias either input.
  - Output source current is supplied through a resistor to ground.
  - Output sink current is supplied through a resistor to  $V_2^+$ .
  - These limits are guaranteed by Gate Output Voltage ( $V_{0o}$ ) test.
  - These limits are guaranteed by Gate Output Voltage ( $V_{1o}$ ) tests.
  - Load capacitance includes test fixture and probe capacitance.
  - Differential Input Voltage = 500mV for this test.
  - Acceptance Test Subgroup A-7 provides end point parameters for linear devices processed to Signetics SURE Program. See Signetics SURE Bulletin 5001.
  - Manufacturer reserves the right to make design and process changes and improvements.

EQUIVALENT CIRCUIT



### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

The SE/NE 527 is a high speed analog voltage comparator which, for the first time mates state-of-the-art Schottky diode technology with the conventional linear process. This allows simultaneous fabrication of high speed T<sup>2</sup>L gates with a precision linear amplifier on a single monolithic chip.

The SE/NE 527 is similar in design to the Signetics SE/NE 529 voltage comparator except that it incorporates a "Emitter Follower" input stage for extremely low input currents. This opens the door to a whole new range of applications for analog voltage comparators.

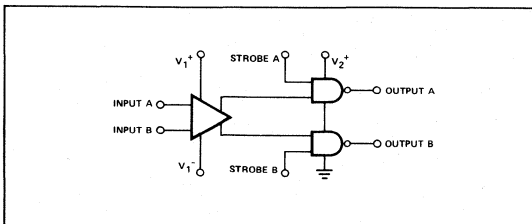
#### FEATURES

- 15 nsec PROPAGATION DELAY
- COMPLEMENTARY OUTPUT GATES
- TTL OR ECL COMPATIBLE OUTPUTS
- WIDE COMMON MODE AND DIFFERENTIAL VOLTAGE RANGE

#### APPLICATIONS

A/D CONVERSION  
 ECL TO TTL INTERFACE  
 TTL TO ECL INTERFACE  
 MEMORY SENSING  
 OPTICAL DATA COUPLING

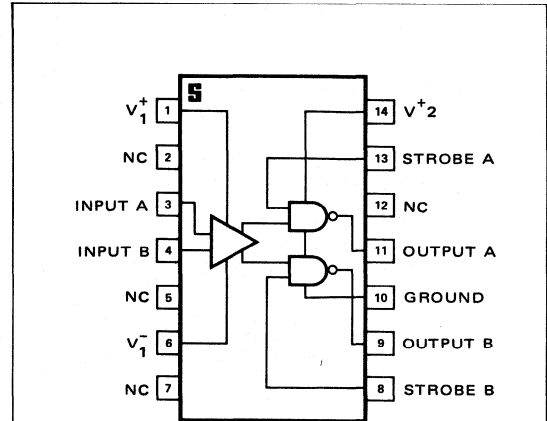
#### BLOCK DIAGRAM



#### ABSOLUTE MAXIMUM RATINGS

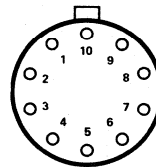
Positive Supply Voltage ( $V_1^+$ )	+15 volts
Negative Supply Voltage ( $V_1^-$ )	-15 volts
Gate Supply Voltage ( $V_2^+$ )	+7 volts
Output Voltage	+15 volts
Differential Input Voltage	$\pm 5$ volts
Input Common Mode Voltage	$\pm 6$ volts
Power Dissipation	600mW
Operating Temperature Range	
NE 527	0°C to +70°C
SE 527	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering 60 seconds)	+300°C

#### PIN CONFIGURATION (TOP VIEW)



ORDER PART NO. SE527A,NE527A

#### K PACKAGE



1. Input A
2. Input B
3.  $V_1^-$
4. Strobe B
5. Output B
6. Ground
7. Output A
8. Strobe A
9.  $V_2^+$
10.  $V_1^+$

ORDER PART NOS. SE527K/NE527K

#### APPLICATIONS

One of the main features of the device is that supply voltages ( $V_1^+$ ,  $V_1^-$ ) need not be balanced, as indicated in the following diagrams. For proper operation, however, negative supply ( $V_1^-$ ) should always be at least six volts more negative than the ground terminal (pin 6). Input Common Mode range should be limited to values of two volts less than the supply voltages ( $V_1^+$  and  $V_1^-$ ) up to a maximum of  $\pm 6$  volts as supply voltages are increased.

It is also important to note that Output A is in phase with Input A and Output B is in phase with Input B.

# SIGNETICS ANALOG VOLTAGE COMPARATOR ■ 527

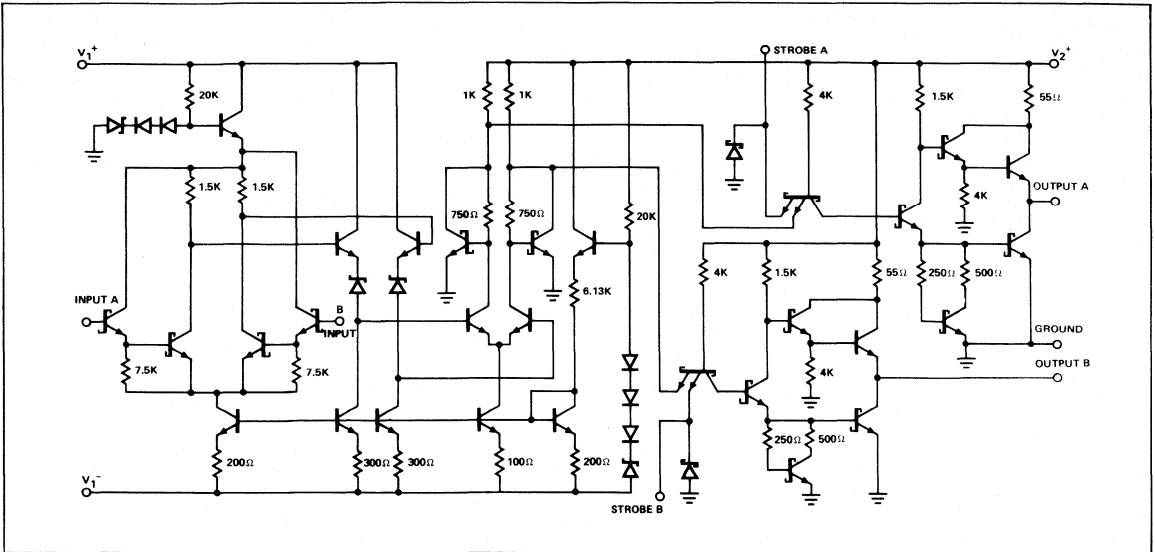
## ELECTRICAL CHARACTERISTICS ( $V_1^+ = +10V$ , $V_1^- = -10V$ , $V_2^+ = +5.0V$ , $V_{in} = 0V$ )

PARAMETER	TEST CONDITIONS	SE 527			NE 527			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
<b>INPUT CHARACTERISTICS</b>								
Input Offset Voltage @25°C				4			6	mV
over temperature range				6			10	mV
Input Bias Current @25°C	$V_1^+ = 10V$ , $V_1^- = -10V$			2			2	$\mu A$
over temperature range	$V_{in} = 0V$			4			4	$\mu A$
Input Offset Current @25°C	$V_1^+ = 10V$ , $V_1^- = -10V$			0.5			0.75	$\mu A$
over temperature range	$V_{in} = 0V$			1			1	$\mu A$
Voltage Gain	$T_A = 25^\circ C$		5			5		V/mV
Input Impedance	$T_A = 25^\circ C$ , $f = 1$ kHz		500			500		K $\Omega$
<b>GATE CHARACTERISTICS</b>								
Output Voltage								
"1" State	$V_2^+ = 4.75V$ , $I_{source} = -1mA$	2.5	3.3		2.7	3.3		V
"0" State	$V_2^+ = 4.75V$ , $I_{sink} = 10mA$			0.5			0.5	V
Strobe Inputs								
"0" Input Current	$V_2^+ = 5.25V$ , $V_{strobe} = 0.5V$			-2			-2	mA
"1" Input Current @25°C	$V_2^+ = 5.25V$ , $V_{strobe} = 2.7V$			50			100	$\mu A$
over temperature range				200			200	$\mu A$
"0" Input Voltage	$V_2^+ = 4.75V$			0.8			0.8	V
"1" Input Voltage	$V_2^+ = 4.75V$	2.0			2.0			V
Short Circuit								
Output Current	$V_2^+ = 5.25V$ , $V_{out} = 0V$	-40		-100	-40		-100	mA
<b>POWER SUPPLY REQUIREMENTS</b>								
Supply Voltage								
$V_1^+$		5		10	5		10	V
$V_1^-$		-6		-10	-6		-10	V
$V_2^+$		4.5	5	5.5	4.75	5	5.25	V
Supply Current	$V_1^+ = 10V$ , $V_1^- = -10V$							
$I_1^+$	$V_2^+ = 5.25V$			3.25				mA
	$T_A = 125^\circ C$			3.75				mA
	$T_A = 25^\circ C$			4.0				mA
	$T_A = -55^\circ C$						5	mA
	$0^\circ C \leq T_A \leq 70^\circ C$							mA
$I_1^-$	$T_A = 125^\circ C$			7.0				mA
	$T_A = 25^\circ C$			7.5				mA
	$T_A = -55^\circ C$			8.5				mA
	$0^\circ C \leq T_A \leq 70^\circ C$						10	mA
$I_2^+$	$T_A = 125^\circ C$			15				mA
	$T_A = 25^\circ C$			16				mA
	$T_A = -55^\circ C$			18				mA
	$0^\circ C \leq T_A \leq 70^\circ C$						20	mA
<b>TRANSIENT RESPONSE</b>								
	$V_{in} = 50$ mV overdrive							
Propagation Delay Time								
$t_{pd}(0)$	$T_A = +25^\circ C$		14	24		14	24	ns
$t_{pd}(1)$	$T_A = +25^\circ C$		16	26		16	26	ns
Delay between Output A and B	$T_A = +25^\circ C$		2	5		2	5	ns
Strobe Delay Time								
Turn On	$T_A = +25^\circ C$	4	6		6			ns
Turn Off	$T_A = +25^\circ C$		6		6			ns

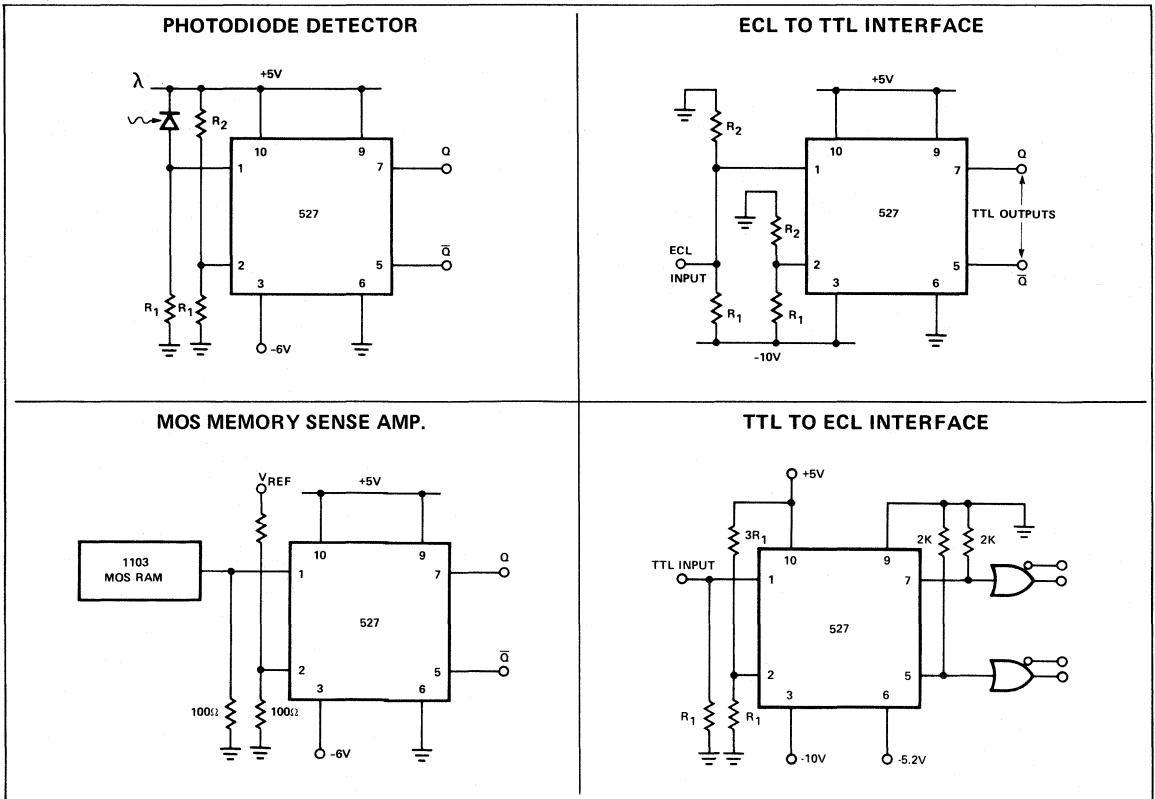
Parameters are guaranteed over the temperature range unless otherwise noted.



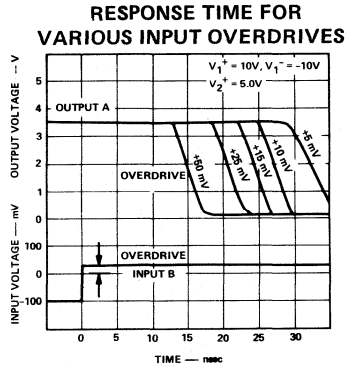
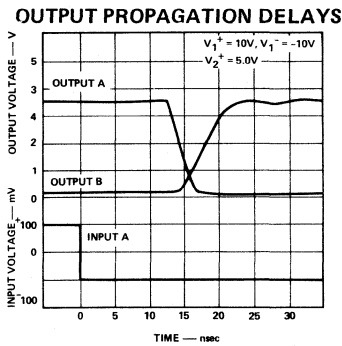
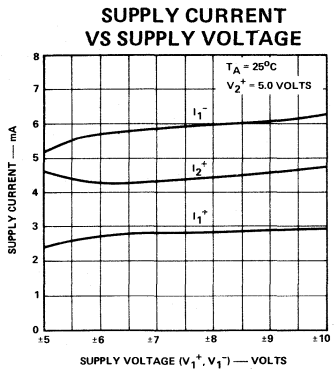
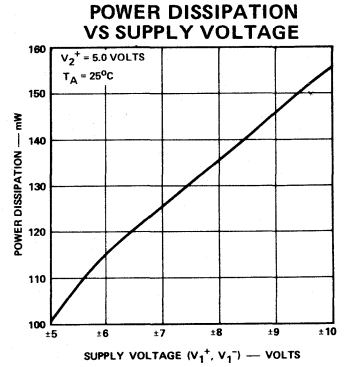
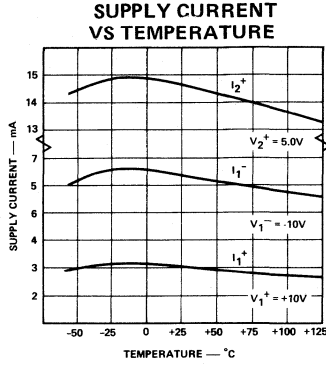
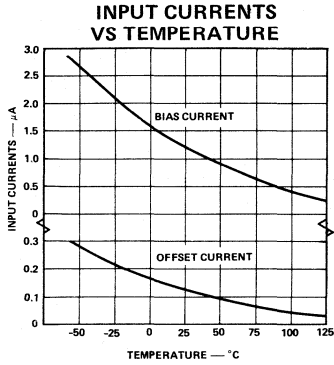
EQUIVALENT CIRCUIT



TYPICAL APPLICATIONS



TYPICAL PERFORMANCE CURVES



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The SE/NE 529 is a high speed analog voltage comparator which, for the first time mates state-of-the-art Schottky diode technology with the conventional linear process. This allows simultaneous fabrication of high speed T<sup>2</sup>L gates with a precision linear amplifier on a single monolithic chip.

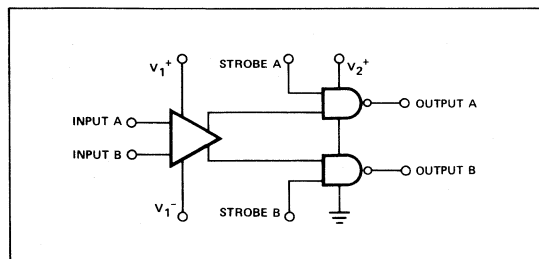
### FEATURES

- 10 nsec PROPAGATION DELAY
- COMPLEMENTARY OUTPUT GATES
- TTL OR ECL COMPATIBLE OUTPUTS
- WIDE COMMON MODE AND DIFFERENTIAL VOLTAGE RANGE

### APPLICATIONS

- A/D CONVERSION
- ECL TO TTL INTERFACE
- TTL TO ECL INTERFACE
- MEMORY SENSING
- OPTICAL DATA COUPLING

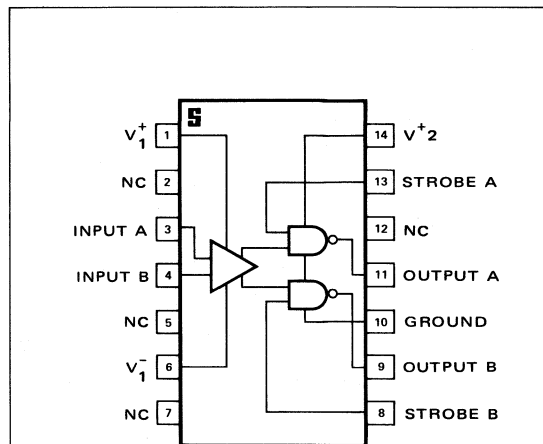
### BLOCK DIAGRAM



### ABSOLUTE MAXIMUM RATINGS

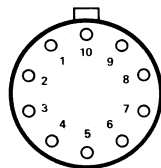
Positive Supply Voltage ( $V_1^+$ )	+15 volts
Negative Supply Voltage ( $V_1^-$ )	-15 volts
Gate Supply Voltage ( $V_2^+$ )	+7 volts
Output Voltage	+15 volts
Differential Input Voltage	±5 volts
Input Common Mode Voltage	±6 volts
Power Dissipation	600mW
Operating Temperature Range	
NE 529	0°C to +70°C
SE 529	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering 60 seconds)	+300°C

### PIN CONFIGURATIONS (TOP VIEW)



ORDER PART NO. SE529A, NE529A

### K PACKAGE



1. Input A
2. Input B
3.  $V_1^-$
4. Strobe B
5. Output B
6. Ground
7. Output A
8. Strobe A
9.  $V_2^+$
10.  $V_1^+$

ORDER PART NOS. SE529K/NE529K

### APPLICATIONS

One of the main features of the device is that supply voltages ( $V_1^+$ ,  $V_1^-$ ) need not be balanced, as indicated in the following diagrams. For proper operation, however, negative supply ( $V_1^-$ ) should always be at least five volts more negative than the ground terminal (pin 6). Input Common Mode range should be limited to values of two volts less than the supply voltages ( $V_1^+$  and  $V_1^-$ ) up to a maximum of ±6 volts as supply voltages are increased.

It is also important to note that Output A is in phase with Input A and Output B is in phase with Input B.

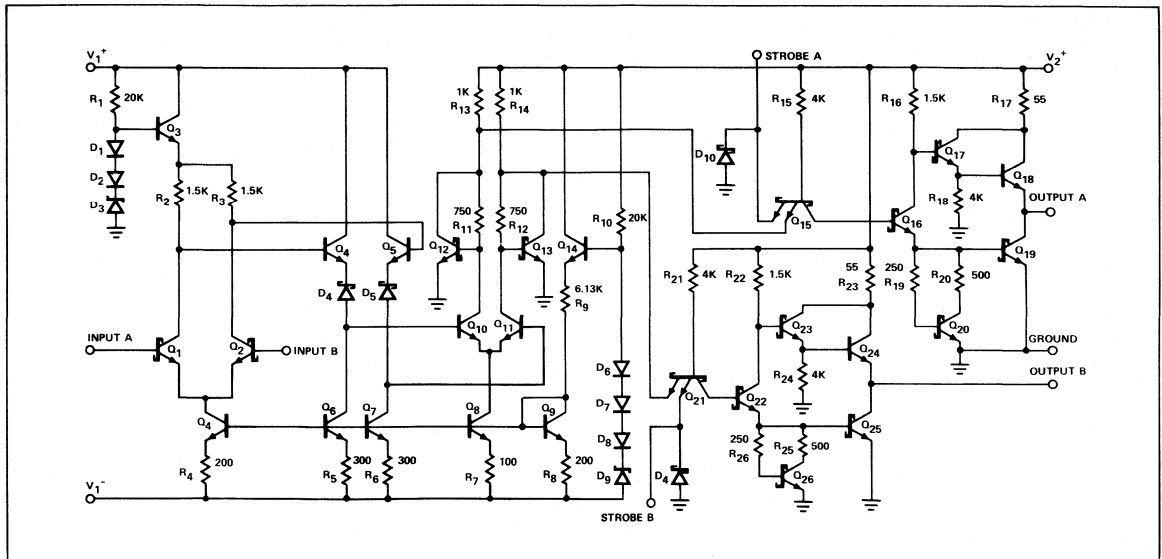
**SIGNETICS ANALOG VOLTAGE COMPARATOR ■ 529**

**ELECTRICAL CHARACTERISTICS** ( $V_1^+ = +10V$ ,  $V_2^+ = +5.0V$ ,  $V_1^- = -10V$ ,  $V_{in} = 0V$ )

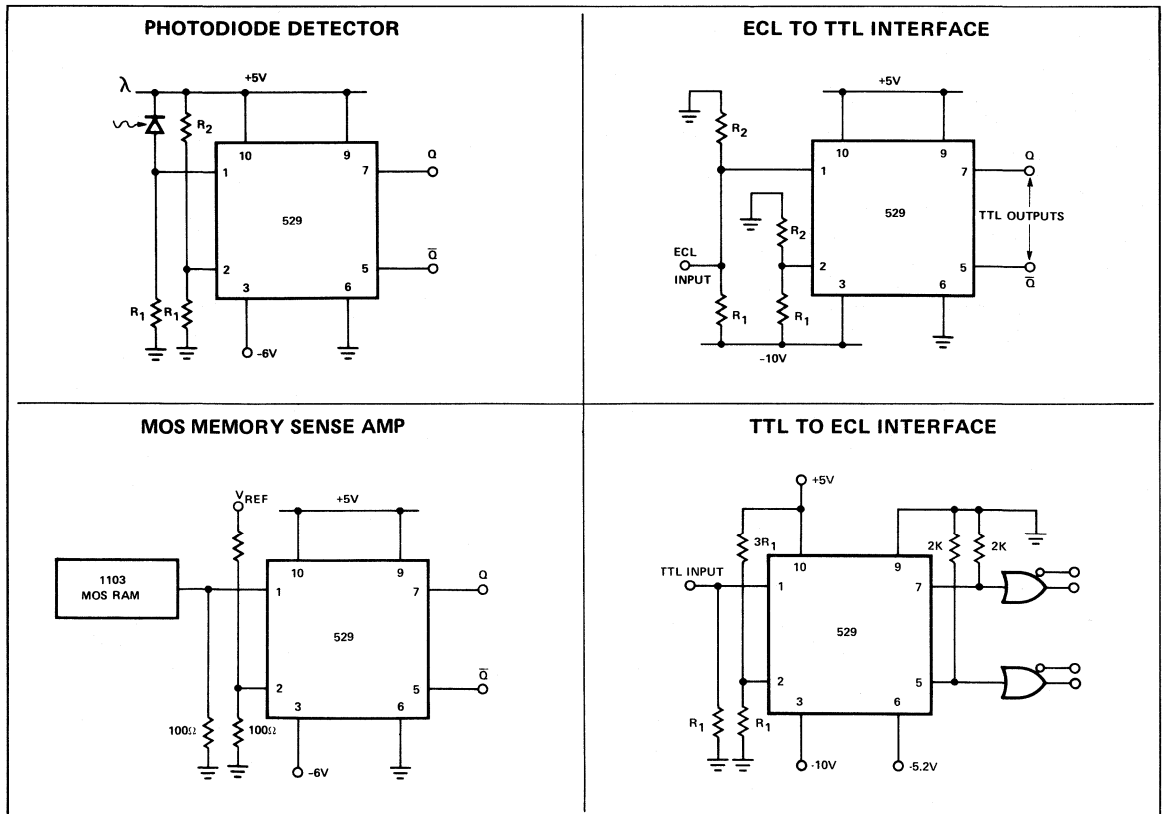
PARAMETER	TEST CONDITIONS	SE 529			NE 529			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
<b>INPUT CHARACTERISTICS</b>								
Input Offset Voltage @25°C over temperature range				4 6			6 10	mV mV
Input Bias Current @25°C over temperature range	$V_1^+ = 10V$ , $V_1^- = -10V$ $V_{in} = 0V$		5	12 36		5	20 50	$\mu A$ $\mu A$
Input Offset Current @25°C over temperature range	$V_1^+ = 10V$ , $V_1^- = -10V$ $V_{in} = 0V$		2	3 9		2	5 15	$\mu A$ $\mu A$
Voltage Gain	$T_A = 25^\circ C$		5			5		V/mV
Input Impedance	$T_A = 25^\circ C$ , $f = 1\text{ kHz}$		10			10		$k\Omega$
<b>GATE CHARACTERISTICS</b>								
<b>Output Voltage</b>								
"1" State	$V_2^+ = 4.75V$ , $I_{source} = -1mA$	2.5	3.3		2.7	3.3		V
"0" State	$V_2^+ = 4.75V$ , $I_{sink} = 10mA$			0.5			0.5	V
<b>Strobe Inputs</b>								
"0" Input Current	$V_2^+ = 5.25V$ , $V_{strobe} = 0.5V$			-2			-2	mA
"1" Input Current @25°C over temperature range	$V_2^+ = 5.25V$ , $V_{strobe} = 2.7V$			50 200			100 200	$\mu A$ $\mu A$
"0" Input Voltage	$V_2^+ = 4.75V$			0.8			0.8	V
"1" Input Voltage	$V_2^+ = 4.75V$	2.0			2.0			V
<b>Short Circuit</b>								
Output Current	$V_2^+ = 5.25V$ , $V_{out} = 0V$	-40		-100	-40		-100	mA
<b>POWER SUPPLY REQUIREMENTS</b>								
<b>Supply Voltage</b>								
$V_1^+$		5		10	5		10	V
$V_1^-$		-6		-10	-6		-10	V
$V_2^+$		4.5	5	5.5	4.75	5	5.25	V
<b>Supply Current</b>								
$I_1^+$	$V_1^+ = 10V$ , $V_1^- = -10V$ $V_2^+ = 5.25V$ $T_A = 125^\circ C$			3.25				mA
	$T_A = 25^\circ C$			3.75				mA
	$T_A = -55^\circ C$			4.0				mA
	$0^\circ C \leq T_A \leq 70^\circ C$						5	mA
$I_1^-$	$T_A = 125^\circ C$			7.0				mA
	$T_A = 25^\circ C$			7.5				mA
	$T_A = -55^\circ C$			8.5				mA
	$0^\circ C \leq T_A \leq 70^\circ C$						10	mA
$I_2^+$	$T_A = 125^\circ C$			15				mA
	$T_A = 25^\circ C$			16				mA
	$T_A = -55^\circ C$			18				mA
	$0^\circ C \leq T_A \leq 70^\circ C$						20	mA
<b>TRANSIENT RESPONSE</b>								
$V_{in} = 50\text{ mV overdrive}$								
<b>Propagation Delay Time</b>								
$t_{pd}(0)$	$T_A = +25^\circ C$		10	20		10	20	ns
$t_{pd}(1)$	$T_A = +25^\circ C$		12	22		12	22	ns
Delay between Output A and B	$T_A = +25^\circ C$		2	5		2	5	ns
<b>Strobe Delay Time</b>								
Turn On	$T_A = +25^\circ C$		6			6		ns
Turn Off	$T_A = +25^\circ C$		6			6		ns

Parameters are guaranteed over the temperature range unless otherwise noted.

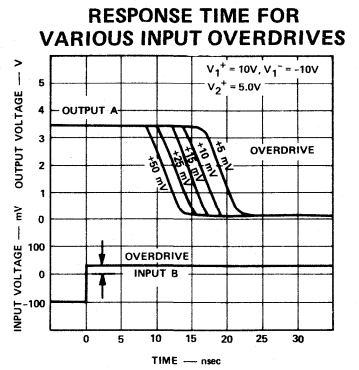
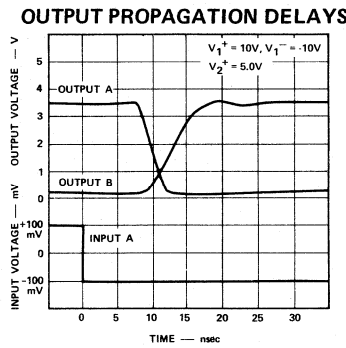
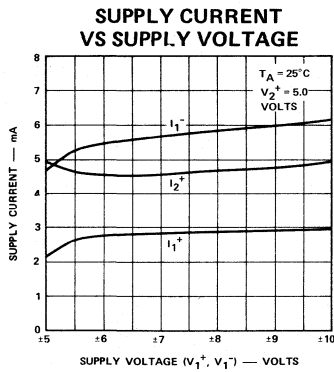
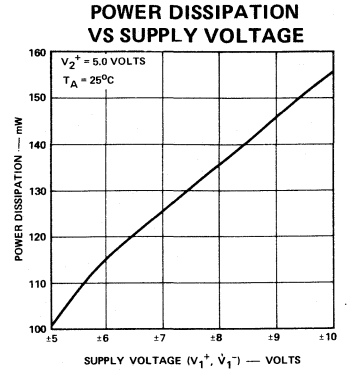
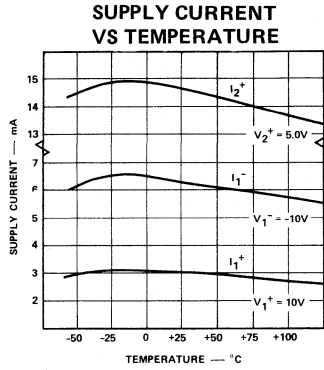
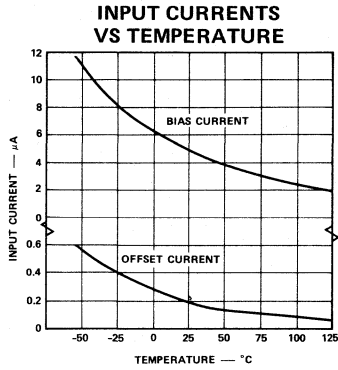
EQUIVALENT CIRCUIT



TYPICAL APPLICATIONS



TYPICAL PERFORMANCE CURVES



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 531 is a fast slewing high performance operational amplifier which retains D.C. performance equal to the best general purpose types while providing far superior large signal A.C. performance. A unique input stage design allows the amplifier to have a large signal response nearly identical to its small signal response. The amplifier can be compensated for truly negligible overshoot with a single capacitor. In applications where fast settling and superior large signal bandwidths are required, the amplifier out performs conventional designs which have much better small signal response. Also, because the small signal response is not extended, no special precautions need be taken with circuit board layout to achieve stability. The high gain, simple compensation and excellent stability of this amplifier allow its use in a wide variety of instrumentation applications.

### FEATURES

- 35V/ $\mu$ sec SLEW RATE AT UNITY GAIN
- PIN FOR PIN REPLACEMENT FOR  $\mu$ A709,  $\mu$ A748 OR LM101
- COMPENSATED WITH A SINGLE CAPACITOR
- SAME LOW DRIFT OFFSET NULL CIRCUITRY AS  $\mu$ A741
- SMALL SIGNAL BANDWIDTH 1 MHz
- LARGE SIGNAL BANDWIDTH 500KHz
- TRUE OP AMP D.C. CHARACTERISTICS MAKE THE 531 THE IDEAL ANSWER TO ALL SLEW RATE LIMITED OPERATIONAL AMPLIFIER APPLICATIONS.

### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	$\pm 22V$
Internal Power Dissipation (Note 1)	300mW
Differential Input Voltage	$\pm 15V$
Common Mode Input Voltage (Note 2)	$\pm 15V$
Voltage Between Offset Null and $V^-$	$\pm 0.5V$
Operating Temperature Range	

NE531	$0^\circ C$ to $+70^\circ C$
SE531	$-55^\circ C$ to $+125^\circ C$

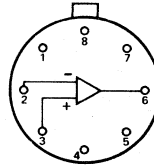
Storage Temperature Range	$-65^\circ C$ to $+150^\circ C$
Lead Temperature (Solder, 60 sec.)	$300^\circ C$
Output Short Circuit Duration (Note 3)	Indefinite

### NOTES:

1. Rating applies for case temperatures to  $125^\circ C$ , derate linearly at  $6.5mW/^\circ C$  for ambient temperatures above  $+75^\circ C$
2. For supply voltages less than  $\pm 15V$ , the absolute maximum input voltage is equal to the supply voltage.
3. Short circuit may be to ground or either supply. Rating applies to  $+125^\circ C$  case temperature or  $+75^\circ C$  ambient temperature.

### PIN CONFIGURATION (Top View)

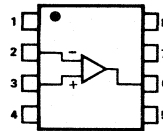
#### T PACKAGE



1. Offset Null
2. Inverting Input
3. Noninverting Input
4.  $V^-$
5. Offset Null
6. Output
7.  $V^+$
8. Freq. Comp.

ORDER PART NOS.  
SE531T/NE531T

#### V PACKAGE

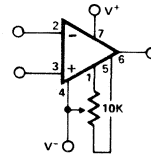


1. Offset Null
2. Inverting Input
3. Noninverting Input
4.  $V^-$
5. Offset Null
6. Output
7.  $V^+$
8. Freq. Comp.

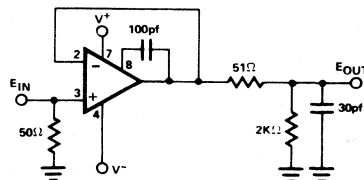
ORDER PART NO. NE531V

### TEST CIRCUITS

#### OFFSET NULL CIRCUIT



#### TRANSIENT RESPONSE TEST CIRCUIT



# SIGNETICS HIGH SLEW RATE OPERATIONAL AMPLIFIER ■ 531

## GENERAL ELECTRICAL CHARACTERISTICS ( $V_S = \pm 15V$ , $T_A = 25^\circ C$ Unless Otherwise Specified)

NE531	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
	Input Offset Voltage	$R_S \leq 10K\Omega$		2.0	6	mV
	Input Offset Current			50	200	nA
	Input Bias Current			0.4	1.5	$\mu A$
	Input Resistance			20		$M\Omega$
	Input Voltage Range		$\pm 10$			Volts
	Common Mode Rejection Ratio	$R_S \leq 10K\Omega$	70	100		dB
	Supply Voltage Rejection Ratio	$R_S \leq 10K\Omega$		10	150	$\mu V/V$
	Large Signal Voltage Gain	$R_L \geq 2K\Omega, V_{OUT} = \pm 10V$	20,000	60,000		
	Output Resistance			75		$\Omega$
	Supply Current			5.5	10	mA
	Power Consumption			165	300	mW
	Full Power Bandwidth			500		KHz
	Settling Time, 1%	$A_V = +1, V_{IN} = \pm 10V$		1.5		$\mu sec$
	Settling Time, .01%	$A_V = +1, V_{IN} = \pm 10V$		2.5		$\mu sec$
	Large Signal Overshoot	$A_V = +1, V_{IN} = \pm 10V$		2		%
	Small Signal Overshoot	$A_V = +1, V_{IN} = 400mV$		5		%
	Small Signal Risetime	$A_V = +1, V_{IN} = 400mV$		300		nsec
	The Following Apply for $0^\circ C < T_A < +70^\circ C$ :					
	Input Offset Voltage	$R_S \leq 10K\Omega$			7.5	mV
	Input Offset Current	$T_A = +70^\circ C$			200	nA
		$T_A = 0^\circ C$			300	nA
	Input Bias Current	$T_A = +70^\circ C$			1.5	$\mu A$
		$T_A = 0^\circ C$			2.0	$\mu A$
	Large Signal Voltage Gain	$R_L \geq 2K\Omega, V_{OUT} = \pm 10V$	15,000			
	Output Voltage Swing	$R_L \geq 2K\Omega$	$\pm 10$	$\pm 13$		Volts
	Slew Rate	$A_V = 100$		35		$V/\mu s$
		$A_V = 10$		35		$V/\mu s$
		$A_V = 1$ (non-inverting)		30		$V/\mu s$
		$A_V = 1$ (inverting)		35		$V/\mu s$
	Supply Current	$T_A = +70^\circ C$		4.5	5.5	mA

SE531	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
	Input Offset Voltage	$R_S \leq 10K\Omega$		2.0	5.0	mV
	Input Offset Current			30	200	nA
	Input Bias Current			300	500	nA
	Input Resistance			20		$M\Omega$
	Input Voltage Range		$\pm 10$			Volts
	Large Signal Voltage Gain	$R_L \geq 2K\Omega, V_{OUT} = \pm 10V$	50,000	100,000		
	Output Resistance			75		$\Omega$
	Supply Current			5.5	7.0	mA
	Power Consumption			165	210	mW
	Full Power Bandwidth			500		KHz
	Settling Time, 1%	$A_V = +1, V_{IN} = \pm 10V$		1.5		$\mu sec$
	Settling Time, .01%	$A_V = +1, V_{IN} = \pm 10V$		2.5		$\mu sec$
	Large Signal Overshoot	$A_V = +1, V_{IN} = \pm 10V$		2		%
	Small Signal Risetime	$A_V = +1, V_{IN} = 400mV$		300		nsec
	Small Signal Overshoot	$A_V = +1, V_{IN} = 400mV$		5		%
	Slew Rate	$A_V = 100$		35		$V/\mu s$
		$A_V = 10$		35		$V/\mu s$
		$A_V = 1$ (non-inverting)	20	30		$V/\mu s$
		$A_V = 1$ (inverting)	25	35		$V/\mu s$
	The following apply for $-55^\circ C < T_A < +125^\circ C$ :					
	Input Offset Voltage	$R_S \leq 10K\Omega$			6	mV
	Input Offset Current	$T_A = +125^\circ C$			200	nA
		$T_A = -55^\circ C$			500	nA
	Input Bias Current	$T_A = +125^\circ C$			500	nA
		$T_A = -55^\circ C$			1.5	$\mu A$
	Common Mode Rejection Ratio	$R_S \leq 10K\Omega$	70	90		dB
	Supply Voltage Rejection Ratio	$R_S \leq 10K\Omega$		10	150	$\mu V/V$
	Large Signal Voltage Gain	$R_L \geq 2K\Omega, V_{OUT} = \pm 10V$	25,000			
	Output Voltage Swing	$R_L \geq 2K\Omega$	$\pm 10$	$\pm 13$		V
	Supply Current	$T_A = +125^\circ C$		4.5	5.5	mA

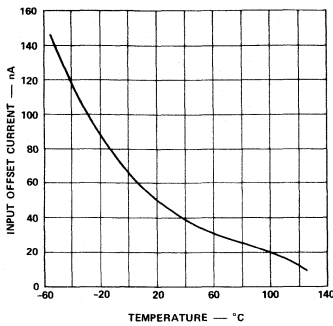
### NOTES:

All AC parametric testing is performed using the conditions of the transient response test circuit, page 1.

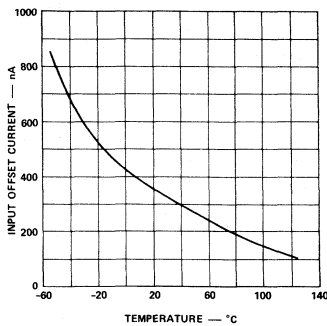


TYPICAL PERFORMANCE CHARACTERISTICS ( $V_S = \pm 15V$ ,  $T_A = +25^\circ C$  unless otherwise noted)

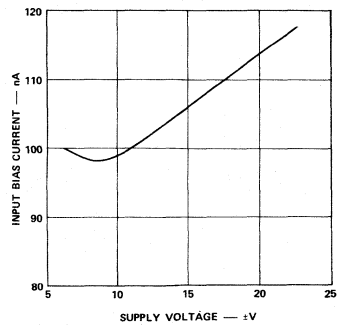
**INPUT OFFSET CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



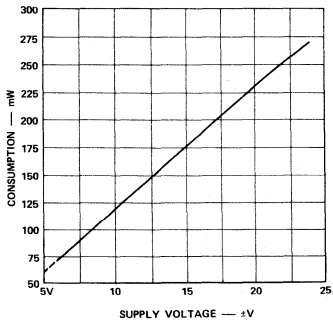
**INPUT BIAS CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



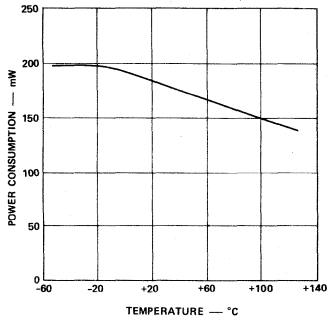
**INPUT BIAS CURRENT AS A FUNCTION OF SUPPLY VOLTAGE**



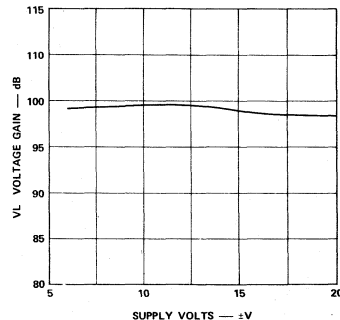
**POWER CONSUMPTION AS A FUNCTION OF SUPPLY VOLTAGE**



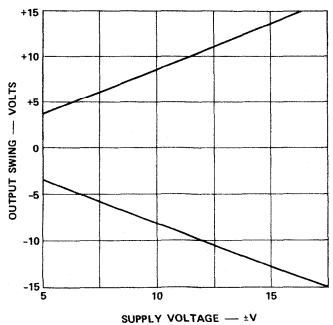
**POWER CONSUMPTION AS A FUNCTION OF AMBIENT TEMPERATURE**



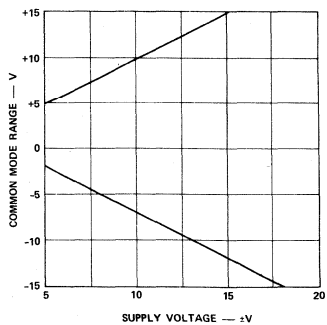
**OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF SUPPLY VOLTAGE**



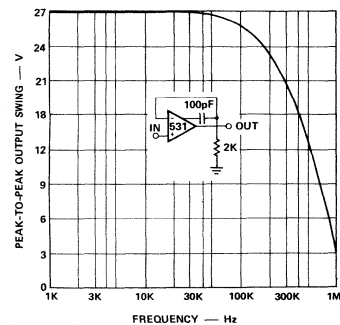
**OUTPUT VOLTAGE SWING AS A FUNCTION OF SUPPLY VOLTAGE**



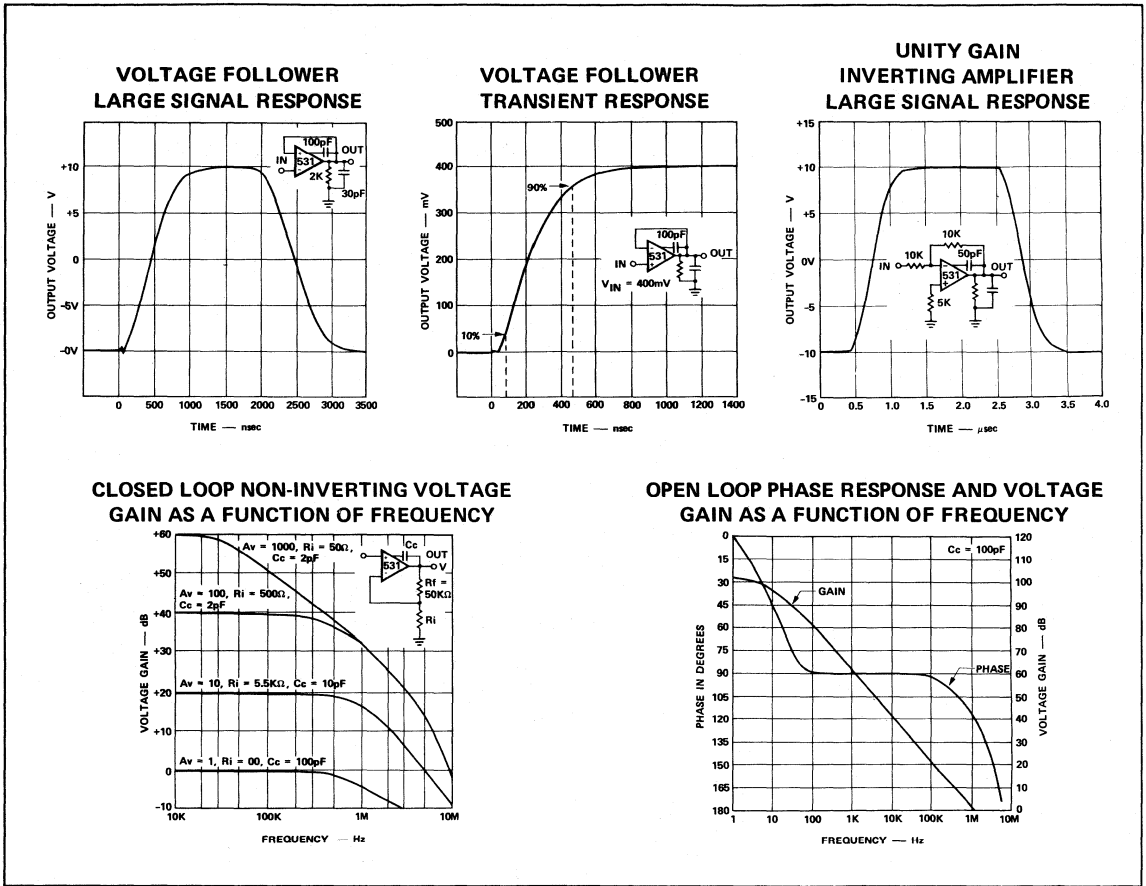
**INPUT VOLTAGE RANGE AS A FUNCTION OF SUPPLY VOLTAGE**



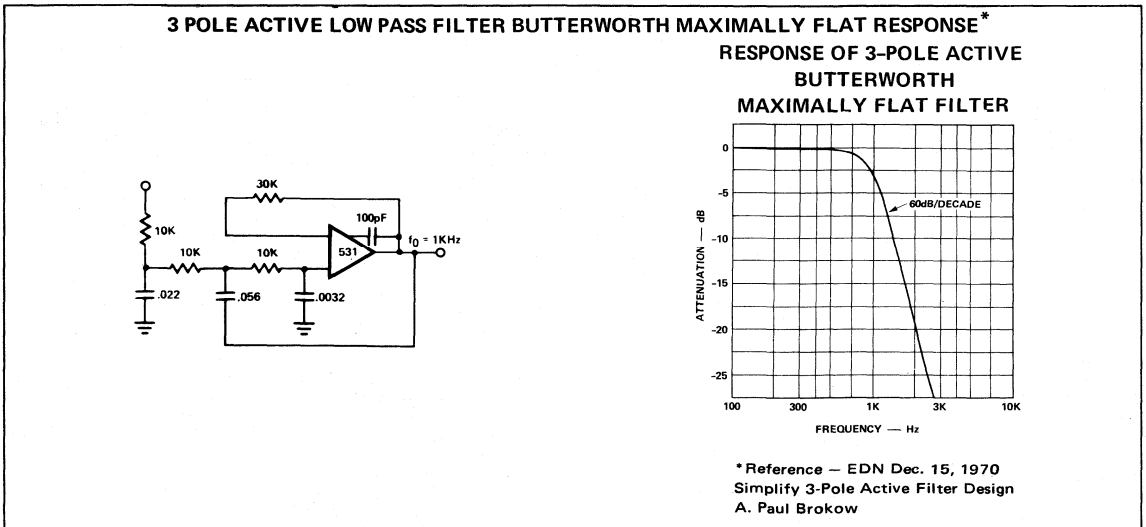
**OUTPUT VOLTAGE SWING AS A FUNCTION OF FREQUENCY**



TYPICAL CHARACTERISTIC CURVES (Cont'd.)

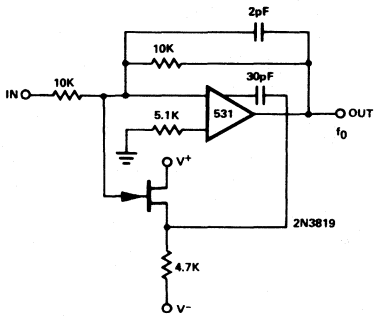


TYPICAL APPLICATIONS



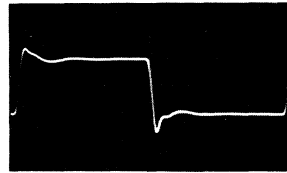
TYPICAL APPLICATIONS (Cont'd.)

HIGH SPEED INVERTER (10MHz Bandwidth)



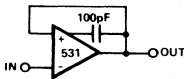
PULSE RESPONSE  
HIGH SPEED INVERTER

0.5V/DIV.



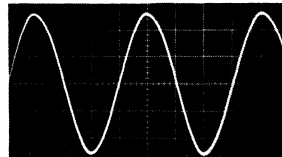
200nsec/DIV

FAST SETTLING VOLTAGE FOLLOWER



LARGE SIGNAL RESPONSE  
VOLTAGE FOLLOWER

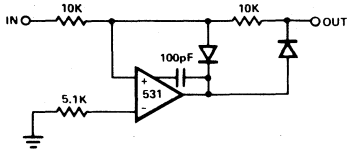
2V/DIV



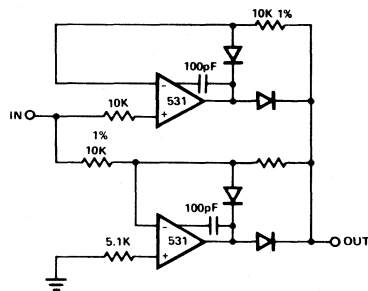
0.5μs/DIV f = 500KHz

PRECISION RECTIFIERS

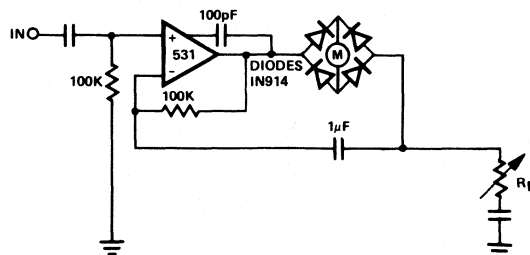
(a) HALF WAVE



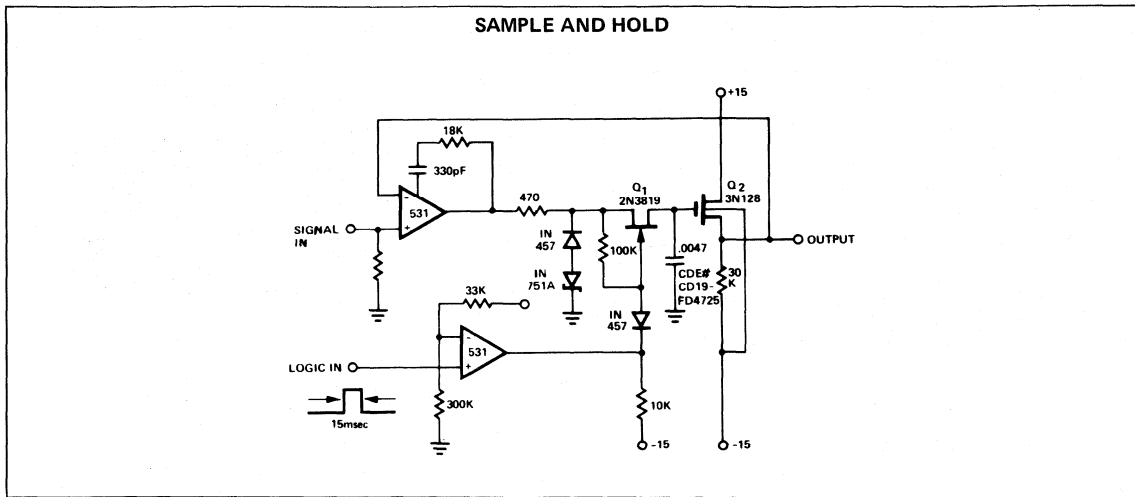
(b) FULL WAVE



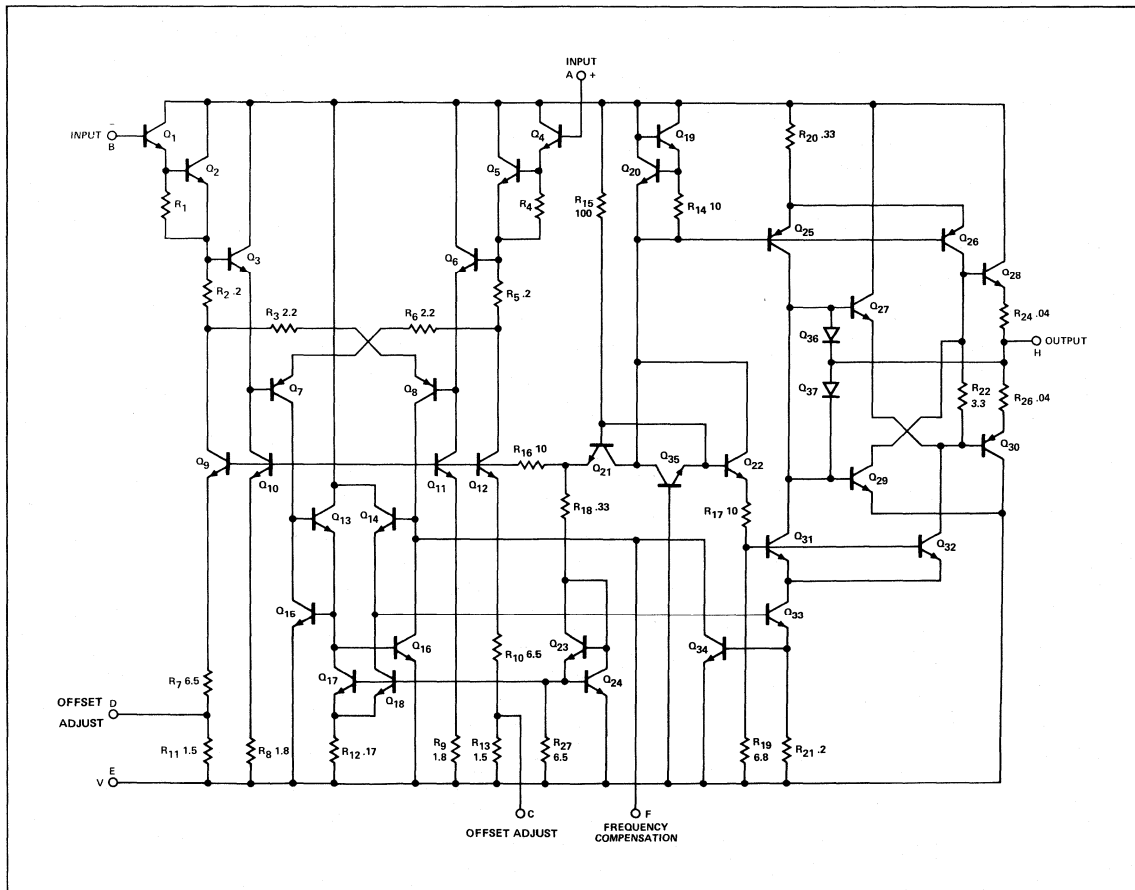
AC MILLIVOLTMETER



TYPICAL APPLICATIONS (Cont'd.)



SCHEMATIC DIAGRAM



### DESCRIPTION

The 536 is a special purpose high performance operational amplifier utilizing a FET input stage for extremely high input impedance and low input current.

The device features internal compensation, standard pinout wide differential and common mode input voltage range, high slew rate and high output drive capability.

### FEATURES

- 5pA INPUT BIAS CURRENT
- INPUT AND OUTPUT PROTECTION
- OFFSET NULL CAPABILITY
- INTERNALLY COMPENSATED
- 6V/ $\mu$ sec SLEW RATE
- STANDARD PINOUT
- 1 MHz UNITY GAIN BANDWIDTH

### MAXIMUM GUARANTEED RATINGS

Supply Voltage	$\pm 22V$
Differential Input Voltage Range	$\pm 30V$
Common Mode Input Voltage Range	$\pm V_s$
Power Dissipation (Note 1)	500mW
Operating Temperature Range	SU536T $-55^\circ C$ to $+85^\circ C$ NE536T $0^\circ C$ to $+70^\circ C$
Storage Temperature Range	$-65^\circ C$ to $+150^\circ C$
Lead Temperature (Solder, 60 sec)	$300^\circ C$
Output Short Circuit Duration (Note 2)	Indefinite

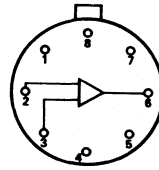
#### NOTES:

1. Rating applies for case temperatures to  $+25^\circ C$ ; derate linearly at  $6.5mW/^\circ C$  for ambient temperatures above  $75^\circ C$ .
2. Short circuit may be to ground or either supply. Rating applies to  $+125^\circ C$  case temperature or  $+75^\circ C$  ambient temperature.

### LINEAR INTEGRATED CIRCUITS

#### PIN CONFIGURATION (Top View)

##### T PACKAGE

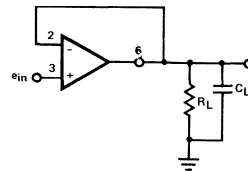


1. Offset Null
2. Inverting Input
3. Non-inverting Input
4.  $V^-$
5. Offset Null
6. Output
7.  $V^+$
8. NC

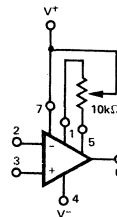
ORDER PART NOS. SU536T/NE536T

#### TEST CIRCUITS

##### VOLTAGE FOLLOWER CIRCUIT



##### OFFSET NULL CIRCUIT



**SIGNETICS FET INPUT OPERATIONAL AMPLIFIER ■ 536**

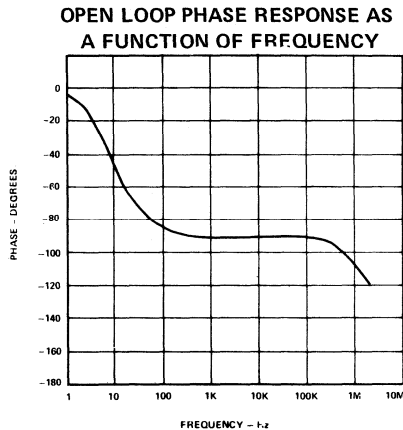
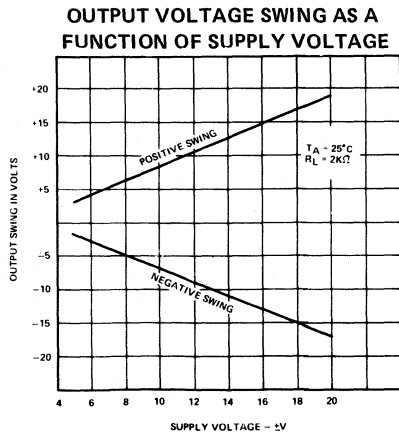
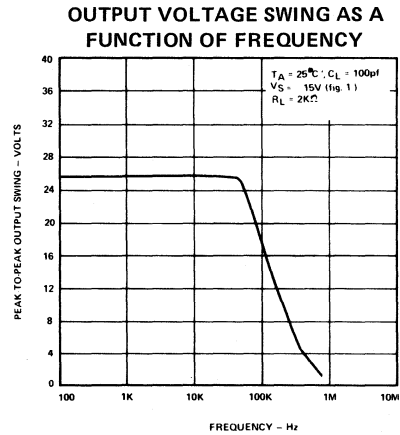
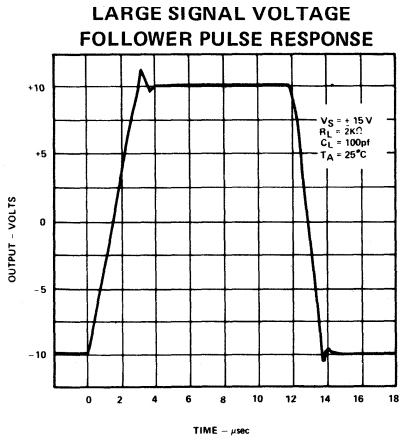
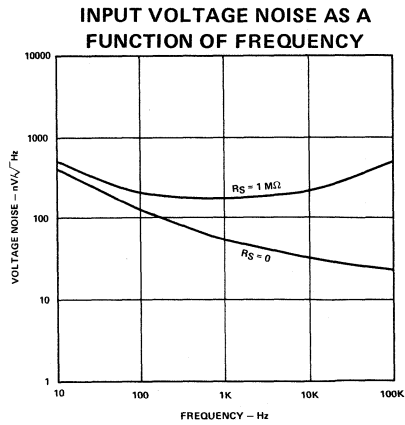
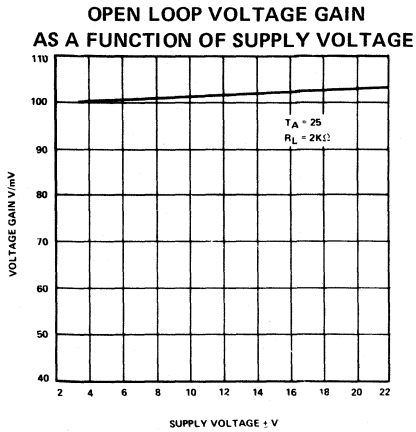
**ELECTRICAL CHARACTERISTICS** (SU536:  $\pm 6V \leq V_S \leq \pm 20V$ ; NE536:  $V_S = \pm 15V$  unless otherwise noted.)

PARAMETER	TEST CONDITIONS	SU536			NE536			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
<b>INPUT CHARACTERISTICS</b>								
Large Signal Voltage Gain @ +25°C Over Temperature Range	$V_S = \pm 15V, V_{OUT} = \pm 10V$ $R_L \geq 2k\Omega$	50	100		50	100		V/mV
		50	100		25	100		V/mV
Input Offset Voltage @ +25°C Over Temperature Range vs Temperature (drift) vs Common Mode Voltage (C.M.R.R.) vs Power Supply (P.S.R.R.)	$V_{IN} = \pm 10V, R_S \leq 10k\Omega$ Note 1, $R_S \leq 10k\Omega$		7.5	20		30	90	mV
			7.5	30		30		mV
			20			30		$\mu V/^\circ C$
			70	80		64	80	dB
Input Current @ +25°C Over Temperature Range vs Temperature (drift)	Either Input		5	30		30	100	pA
			250	3000				pA
		Typ. Doubles Every 10°C						
Input Offset Current @ +25°C Over Temperature (drift)			5			5		pA
Input Impedance Differential Resistance Differential Capacitance	$T_A = +25^\circ C$		10 <sup>14</sup>			10 <sup>14</sup>		$\Omega$
	$T_A = +25^\circ C$		6			6		pF
Input Noise (0.1Hz – 100kHz) Voltage Noise			20			20		$\mu V_{rms}$
Common Mode Voltage Range	$V_S = \pm 15V$	$\pm 10$	$\pm 11$		$\pm 10$	$\pm 11$		V
<b>OUTPUT CHARACTERISTICS</b>								
Output Current	$V_S = \pm 15V$	5			5			mA
Open Loop Output Impedance			100			100		$\Omega$
Output Voltage Swing	$V_S = \pm 15V, R_L \geq 2k\Omega$	$\pm 10$	$\pm 12$		$\pm 10$	$\pm 10$		V
	$V_S = \pm 15V, R_L \geq 10k\Omega$	$\pm 12$	$\pm 13$		$\pm 12$	$\pm 13$		V
Short Circuit Current	$V_S = \pm 15V, T_A = +25^\circ C$		17			17		mA
<b>FREQUENCY AND TRANSIENT RESPONSE</b>								
Gain Bandwidth Product	$V_S = \pm 15V, T_A = +25^\circ C,$ $A = 100$		1			1		MHz
Unity Gain Frequency	$V_S = \pm 15V, T_A = +25^\circ C$		1			1		MHz
Full Power Bandwidth	$V_S = \pm 15V, T_A = +25^\circ V$		100			100		kHz
Slew Rate Inverter Follower	$V_S = \pm 15V, T_A = +25^\circ C, A = -1$		6			6		V/ $\mu s$
	$V_S = \pm 15V, T_A = +25^\circ C, A = +1$		6			6		V/ $\mu s$
<b>POWER SUPPLY REQUIREMENT</b>								
Power Supply Range		$\pm 6$		$\pm 20$	$\pm 6$		$\pm 18$	V
Quiescent Supply Current	$V_S = \pm 20V, V_{OUT} = 0V,$ $T_A = +25^\circ C$		4.5	5.5				mA
	$V_S = \pm 15V, V_{OUT} = 0V,$ $T_A = +25^\circ C$					6.0	8.0	mA
Quiescent Power Dissipation	$V_S = \pm 15V, V_{OUT} = 0V,$ $T_A = +25^\circ C$		180			180		mW

Parameters are tested over temperature range unless otherwise noted.

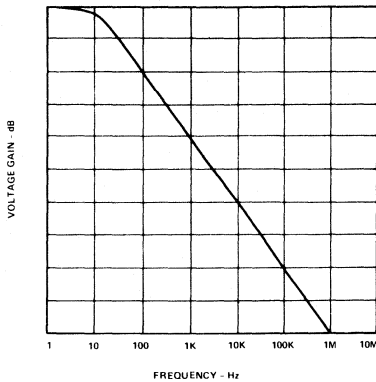
NOTE 1: SU536:  $V_S = \pm 6V$  to  $\pm 20V$   
NE536:  $V_S = \pm 6V$  to  $\pm 15V$

TYPICAL CHARACTERISTIC CURVES

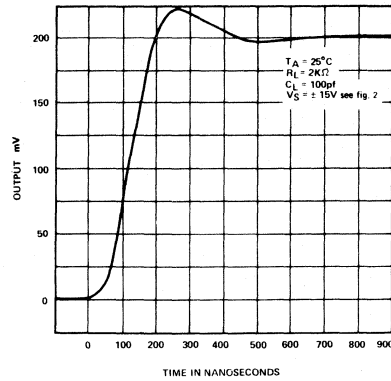


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

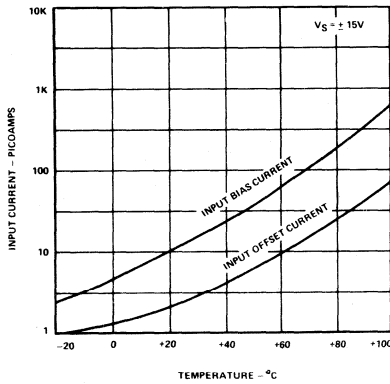
OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF FREQUENCY



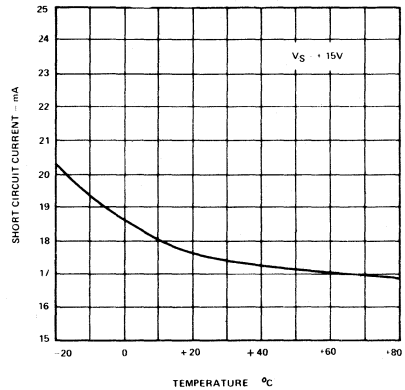
VOLTAGE FOLLOWER TRANSIENT RESPONSE



INPUT CURRENTS AS A FUNCTION OF AMBIENT TEMPERATURE

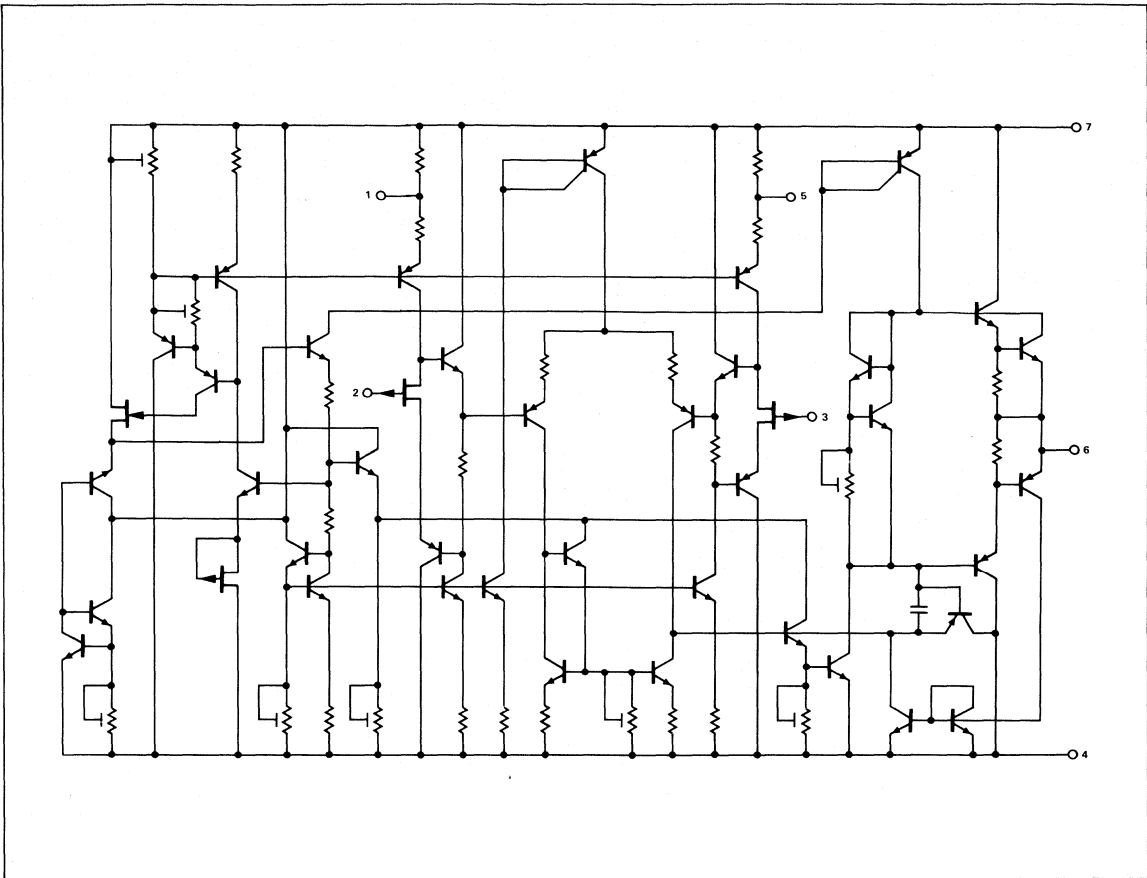


OUTPUT SHORT-CIRCUIT CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE





CIRCUIT SCHEMATIC



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 540 is a monolithic, class AB power amplifier designed specifically to drive a pair of complementary output transistors. The device features low standby current yet retains a high output current drive capability with internal current limiting. A wide power bandwidth and excellent linearity make this device ideal for use as an audio power amplifier.

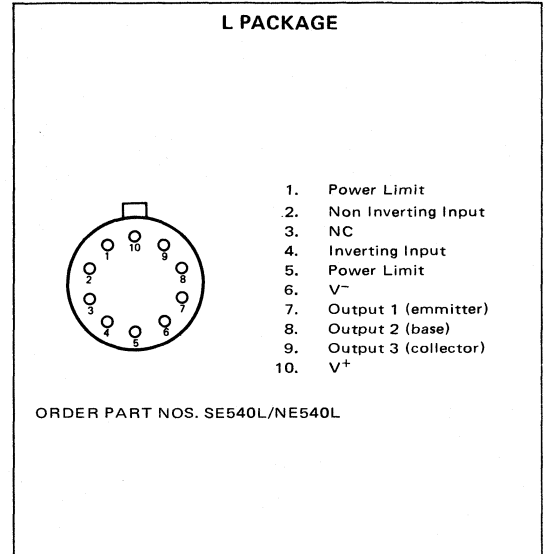
### FEATURES

- INTERNAL CURRENT LIMITING
- LOW STANDBY CURRENT
- HIGH OUTPUT CURRENT CAPABILITY
- WIDE POWER BANDWIDTH
- LOW DISTORTION

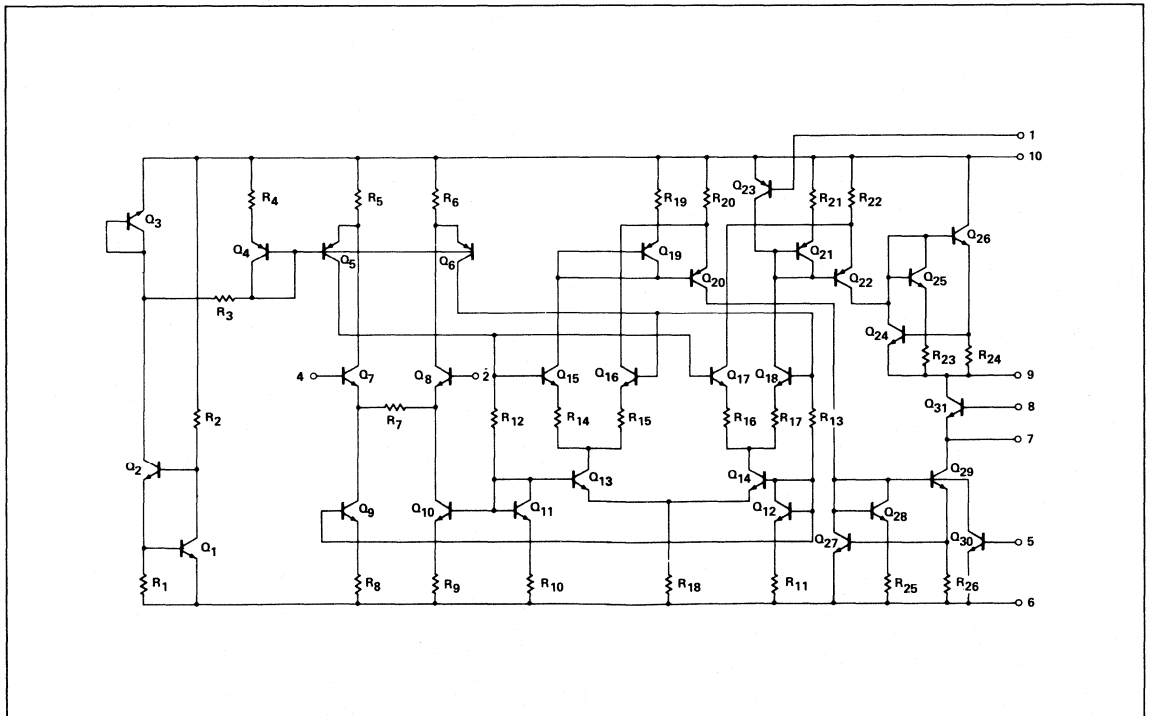
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	± 27 Volts SE540
	± 22 Volts NE540
Operating Temperature Range	-55°C to +125°C SE540
	0°C to +70°C NE540
Storage Temperature Range	-65°C to +150°C
Output Short Circuit Duration	Indefinite
(Not exceeding maximum dissipation.)	

### PIN CONFIGURATION (TOP VIEW)



### SCHEMATIC DIAGRAM

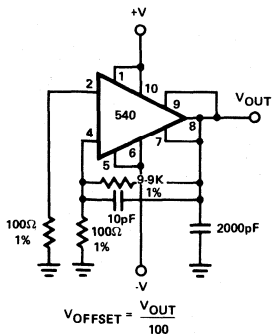


ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

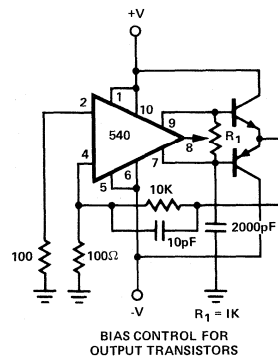
PARAMETER	TEST CONDITIONS	SE 540			NE 540			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	
Operating Temperature Range		-55		+125	0		+70	$^\circ\text{C}$
Operating Supply Voltage		$\pm 5$		$\pm 25$	$\pm 5$		$\pm 20$	Volts
Quiescent Current			13	20		13	20	mA
Input Offset Voltage			5	7		7	10	mV
Input Offset Current			0.3	0.7		0.5	1	$\mu\text{A}$
Input Bias Current			1.5	3		2	5	$\mu\text{A}$
Input Impedance	40 dB Gain		20			20		$\text{k}\Omega$
Current Gain		80	100		70	90		dB
Gain Variation Over Temperature Range	40 dB Gain		$\pm 0.1$			$\pm 0.1$		dB
Frequency Response	40 dB Gain $\pm 1$ dB		500			100		kHz
Distortion	40 dB Gain Output 3 dB below maximum $R_L = 600\Omega$ $R_L = 2\text{K}\Omega$ $R_S = 600\Omega$		0.25	0.5		0.5	1.0	%
Equivalent Input Noise Voltage	50 Hz to 500 kHz		10	0.06		10	0.06	$\mu\text{V}$
Power Supply Rejection Ratio	40 dB Gain	80	90		60	80		dB
Common Mode Rejection Ratio			110			90		dB
Output Drive Current		$\pm 120$	$\pm 150$		$\pm 80$	$\pm 100$		mA
Slew Rate	$V_S = \pm 20\text{V}$ $V_{\text{OUT}} = \pm 15\text{V}$		200			200		$\text{V}/\mu\text{s}$

TEST CIRCUITS

OFFSET VOLTAGE MEASUREMENT

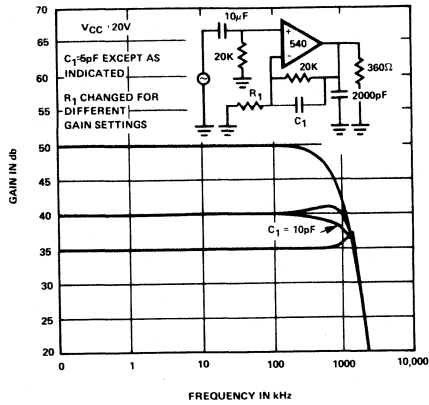


OUTPUT BIAS CONTROL

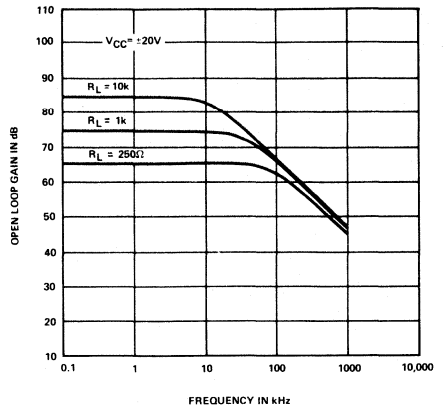


TYPICAL PERFORMANCE CHARACTERISTICS

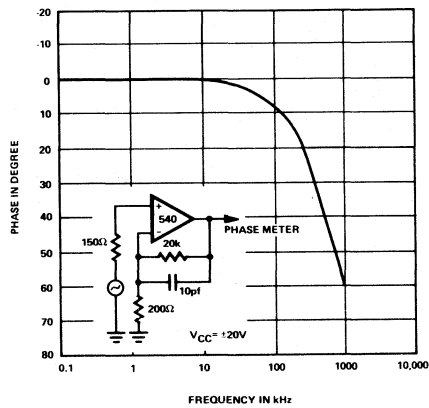
**CLOSED LOOP FREQUENCY RESPONSE**



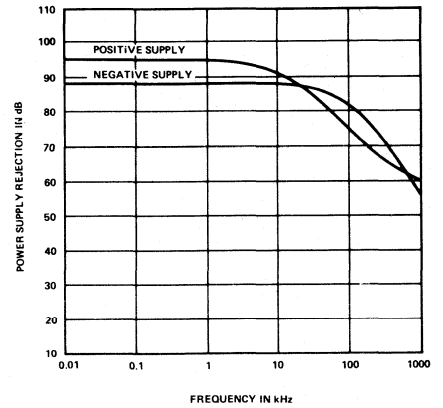
**OPEN LOOP GAIN AND FREQUENCY RESPONSE**



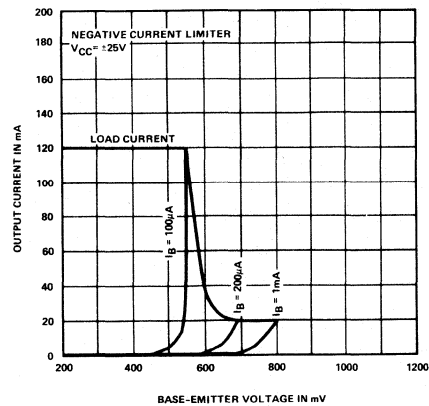
**PHASE RESPONSE VERSUS FREQUENCY**



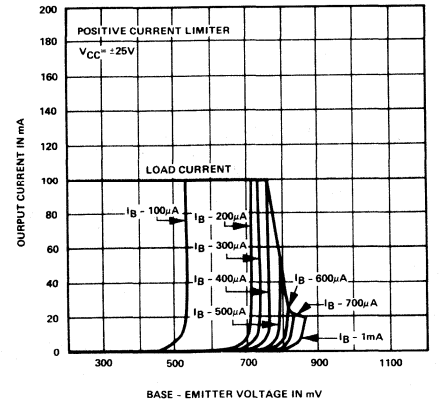
**POWER SUPPLY REJECTION VERSUS FREQUENCY**



**OUTPUT CURRENT VERSUS  $I_B/V_{BE}$  OF CURRENT LIMITER**

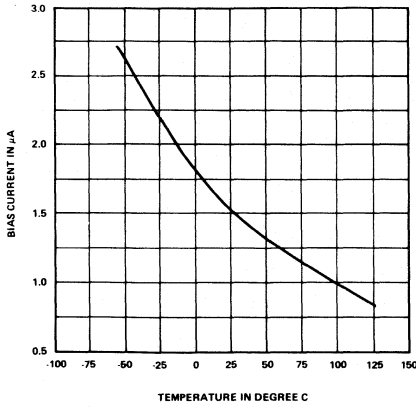


**OUTPUT CURRENT VERSUS  $I_B/V_{BE}$  OF CURRENT LIMITER**

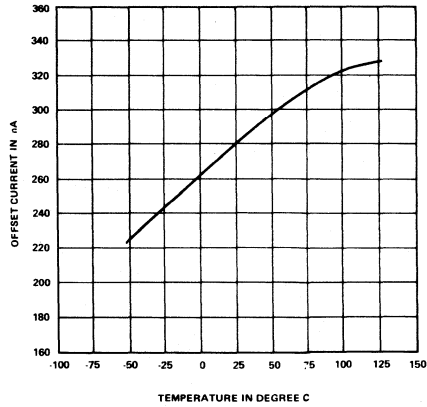


TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd.)

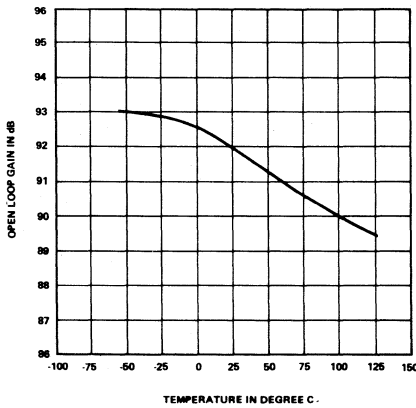
**BIAS CURRENT  
VERSUS TEMPERATURE**



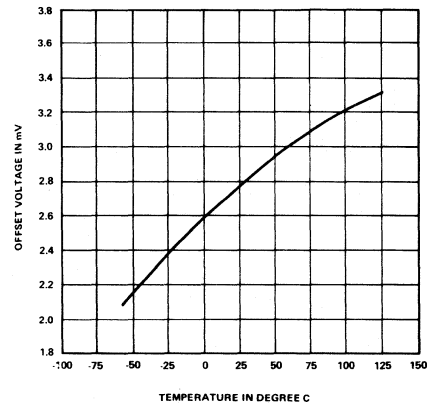
**OFFSET CURRENT  
VERSUS TEMPERATURE**



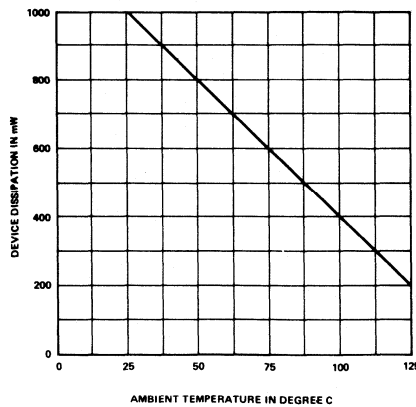
**OPEN LOOP GAIN  
VERSUS TEMPERATURE**



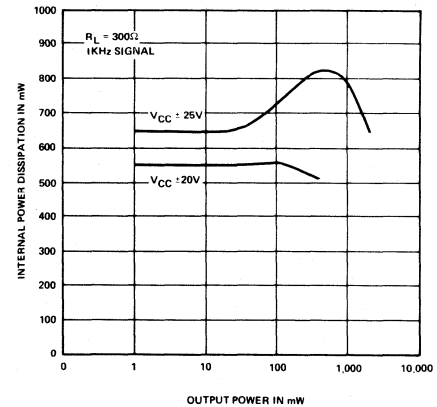
**OFFSET VOLTAGE  
VERSUS TEMPERATURE**



**MAXIMUM DISSIPATION  
VERSUS AMBIENT TEMPERATURE**

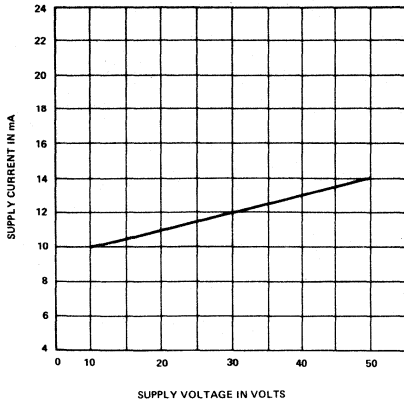


**INTERNAL POWER DISSIPATION  
VERSUS LOAD POWER**

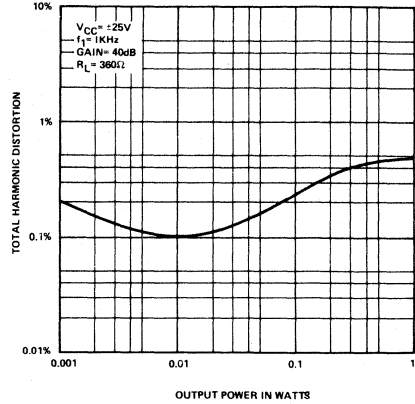


TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd.)

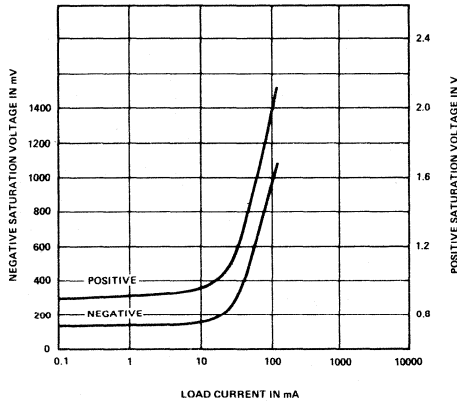
QUIESCENT CURRENT  
VERSUS SUPPLY VOLTAGE



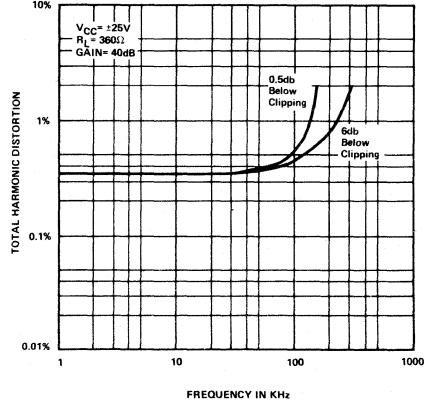
TOTAL HARMONIC DISTORTION  
VERSUS OUTPUT



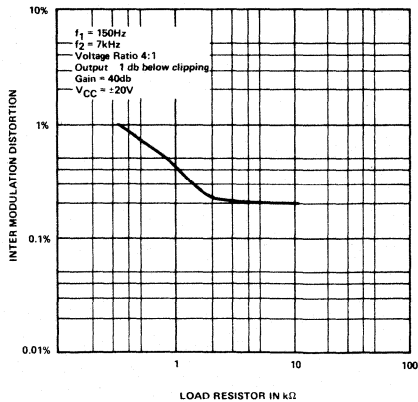
OUTPUT SATURATION VOLTAGE  
VERSUS LOAD



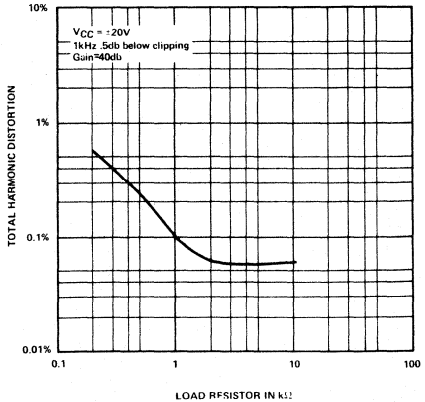
TOTAL HARMONIC DISTORTION  
VERSUS FREQUENCY

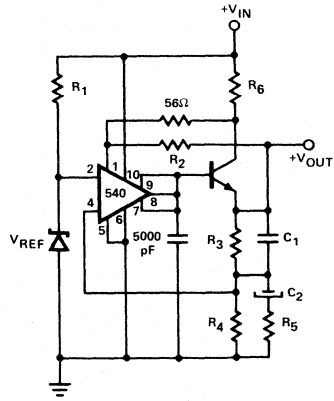
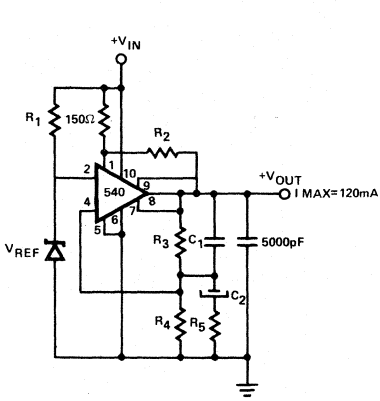


INTERMODULATION DISTORTION  
VERSUS LOAD



TOTAL HARMONIC DISTORTION  
VERSUS LOAD





$$V_{OUT} \approx \frac{R_3 + R_4}{R_4} V_{REF}$$

$$R_1 \approx \frac{V_{IN} \cdot V_{REF}}{I_{ZENER}}$$

$$R_2 \approx \frac{2 V_{IN} \cdot V_{OUT}}{4mA}$$

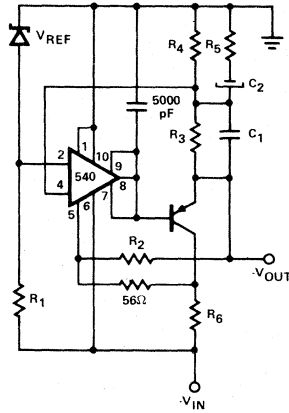
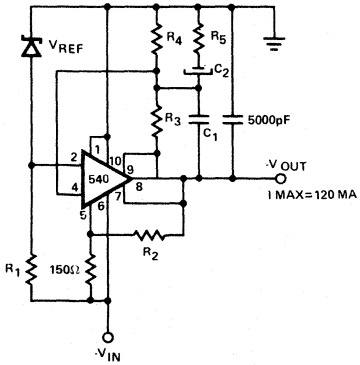
$$V_{REF}$$

$$R_5 \approx \frac{R_3}{100}$$

$$C_1 \approx \frac{0.2}{R_3} \mu F$$

$$C_2 \approx 10 \mu F$$

NEGATIVE VOLTAGE REGULATORS



$$V_{OUT} \approx \frac{R_3 + R_4}{R_4} V_{REF}$$

$$R_1 \approx \frac{V_{IN} \cdot V_{REF}}{I_{ZENER}}$$

$$R_2 \approx \frac{2 V_{IN} \cdot V_{OUT}}{4mA}$$

$$V_{REF}$$

$$R_5 \approx \frac{R_3}{100}$$

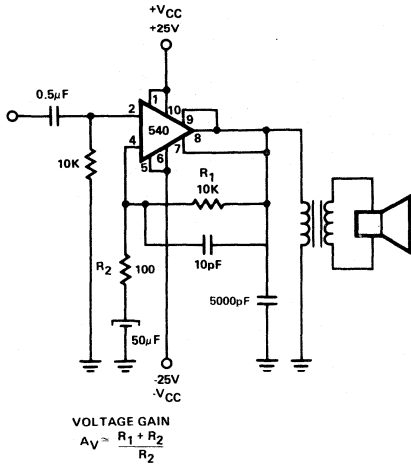
$$C_1 \approx \frac{0.2}{R_3} \mu F$$

$$C_2 \approx 10 \mu F$$

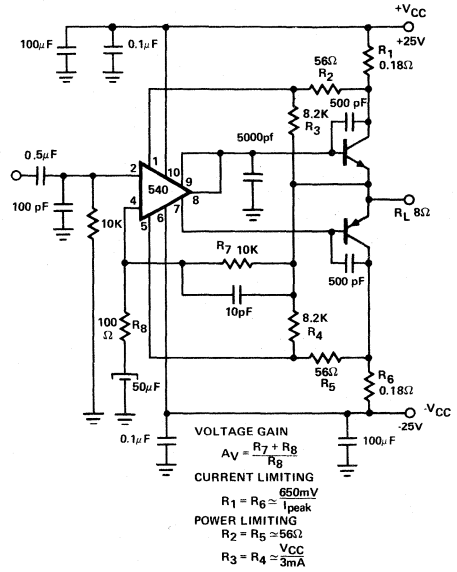
TYPICAL APPLICATIONS

POWER AMPLIFIERS

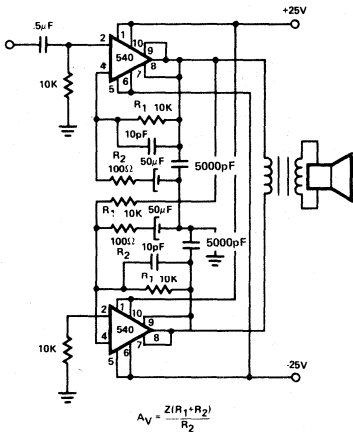
1 Watt



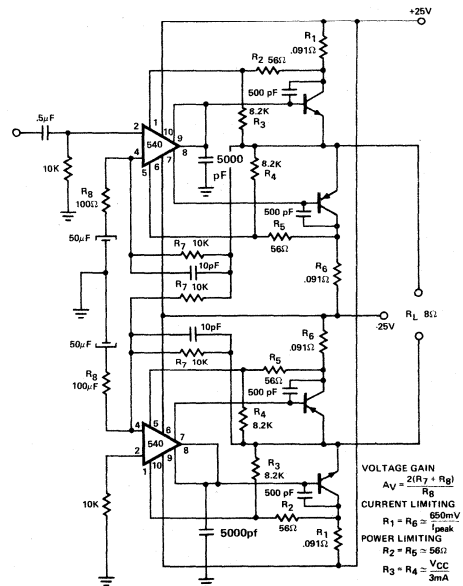
35 Watts



3 Watts



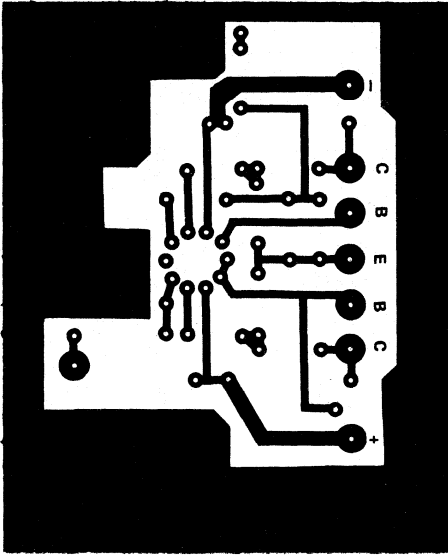
70 Watts



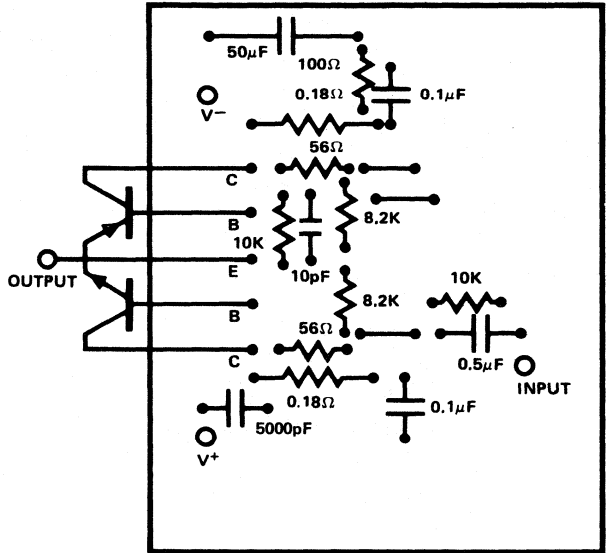


35 WATT AMPLIFIER

P.C. BOARD LAYOUT (BOTTOM VIEW)



PARTS LAYOUT (TOP VIEW)



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE546 is a monolithic integrated circuit that provides an RF amplifier, IF amplifier, mixer, oscillator, AGC detector, and voltage regulator in a single IC. The primary application is super-heterodyne AM radio receiver particularly in automobile radios. The NE546 is available in a 14 lead dual inline package.

### FEATURES

- LOW NOISE
- BUILD IN AGC CIRCUIT
- SEPARATELY ACCESSABLE AMPLIFIERS
- MIXER-OSCILLATOR STAGE WITH INTERNAL FEEDBACK
- HIGH SELECTIVITY
- HIGH IMAGE REJECTION

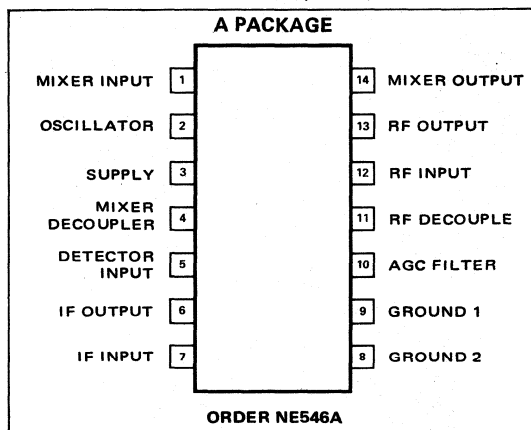
### ABSOLUTE MAXIMUM RATINGS

V <sub>CC</sub> Supply Voltage Pins 3, 13, 14 at Pin 6	16V
DC Supply Voltage (V+)	40V
DC Supply Current	35mA
Internal Power Dissipation (Note 1)	750mW
Lead Temperature	300°C
Operating Temperature Range	-40°C to +85°C
Storage Temperature Range	-65°C to +150°C

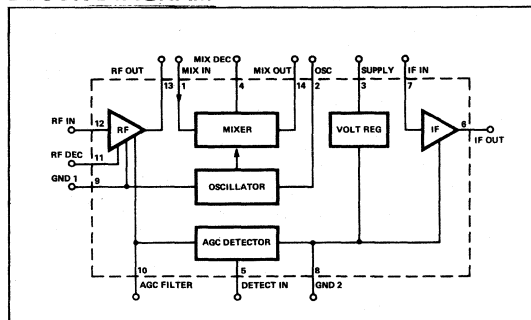
#### NOTE

Rating applies for temperatures up to 55°C. Derate linearly at 6.67mW/°C above 55°C.

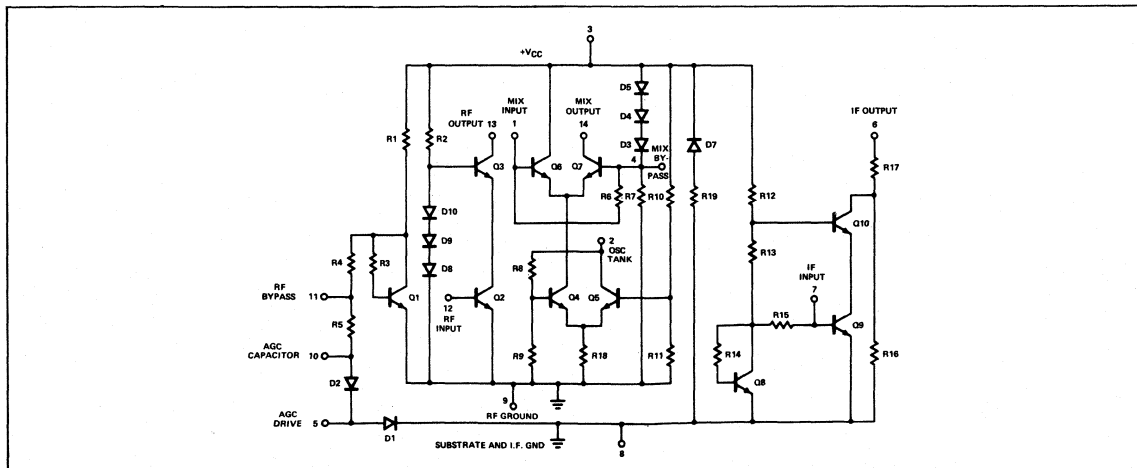
### PIN CONFIGURATION (Top View)



### BLOCK DIAGRAM



### AM RADIO CIRCUIT SCHEMATIC

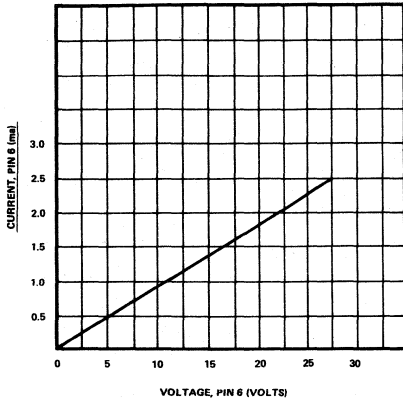


ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$  at  $V_{CC} = 11.0\text{V}$ )

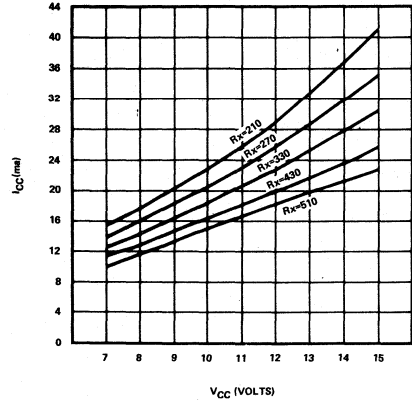
CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
DC Voltage: Supply Voltage	$+V_{CC}$		9.0		15.0	mV
Mixer balance	$V_{OS} (V_1-V_4)$			1.0	10	
Zener voltage	$V_3$		5.5	6.0	7.0	V
At Terminal 5 AGC voltage	$V_5$		0.1	0.25	0.4	V
Pin 7 voltage	$V_7$		0.55	0.70	0.80	V
Pin 12 voltage	$V_{12}$		0.6	0.71	0.8	V
Pin 13 voltage	$V_{13}$			4.0		V
DC Current: Supply current	$I_{CC}$		15	18	22	mA
Oscillator current	$I_2$			1.0		mA
Zener current	$I_3$		12	14	16	mA
IF current	$I_6$		3.5	4.3	6	mA
RF current	$I_{13}$			4.0	5	mA
Mixer current	$I_{14}$			0.17	0.38	mA
Static: I.F. breakdown & linearity	$V_6$	Apply 5 volts to Pin 6 only. $V_{CC} = 0$ volts. Measure $I_{Pin 6}$	400	500	600	$\mu\text{A}$
I.F. breakdown & linearity	$V_6$	Apply 25 volts to Pin 6 only. $V_{CC} = 0$ volts. Measure $I_{Pin 6}$ . Note: Linearity @ 25V should be within 5% of linearity @ 5V.	2.0	2.5	3.0	mA
Performance Characteristics in Circuit of Figure 3						
Saturation		Per sensitivity test interrupting input signal measure output voltage.	500			mV
Sensitivity		Input Signal to Dummy Antenna at $f_{IN} =$ 1 MHz, 30% AM Modulation at $f_{MOD} =$ 400 Hz, for 11 mV output at $V_O$ .		2.5	5	$\mu\text{V}$
Signal-to-Noise Ratio	S/N	Ratio of Output at $V_O$ with Modulation ON and then OFF, Input Signal = $100\mu\text{V}$ , 30% AM Modulation at $f_{MOD} = 400$ Hz.	34	40		dB
Overload Distortion		Input Signal set at 1 MHz, 90% AM Modu- lation, Distortion at $V_O$ must be $\leq 10\%$	100	155	250	mV
Dynamic Characteristics for Indicated Stages in Circuit of Figure 3						
STAGE	PARALLEL CAPACITANCE		PARALLEL RESISTANCE		TRANSCONDUCTANCE	
	INPUT pF	OUTPUT pF	INPUT $\Omega$	OUTPUT $\Omega$	AT 1 MHz CARRIER $\mu\text{mhos}$	
RF Amplifier	20	6	670	$2 \times 10^6$ min	150,000 @ 1 MHz	
IF Amplifier	35	3.5	850	$10^4$	100,000 @ 262.5 kHz	
Mixer	4	2	2000	$2 \times 10^6$ min	10,000	

TYPICAL CHARACTERISTICS

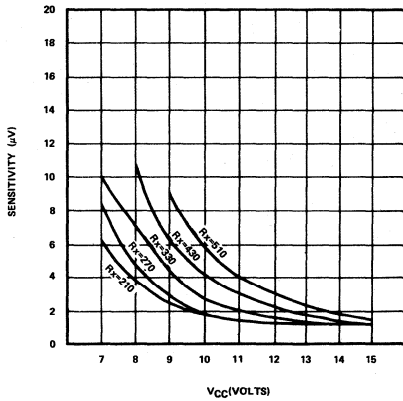
IF OUTPUT LINEARITY



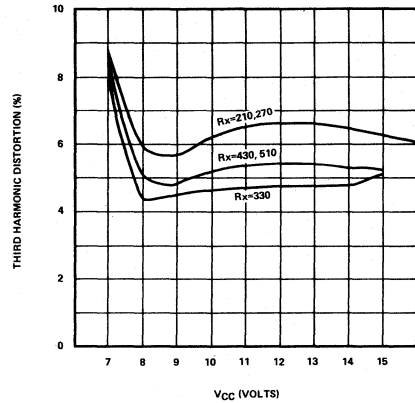
ICC VS. SUPPLY VOLTAGE



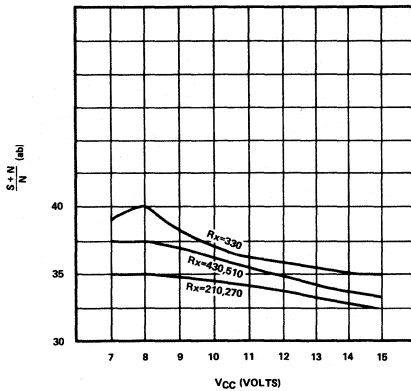
SENSITIVITY VS. SUPPLY VOLTAGE



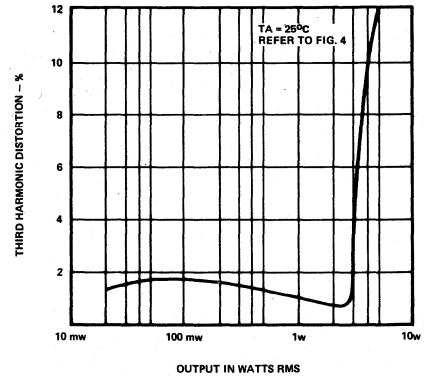
THIRD HARMONIC DISTORTION VS. SUPPLY VOLTAGE



SIGNAL TO NOISE VS. SUPPLY VOLTAGE



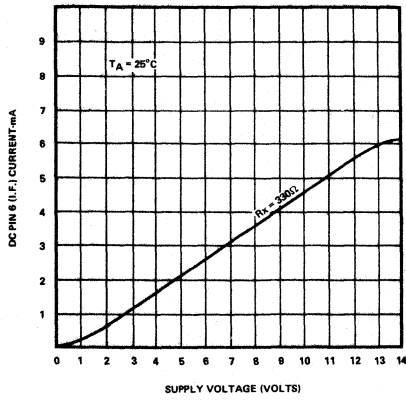
THIRD HARMONIC DISTORTION VERSUS OUTPUT POWER



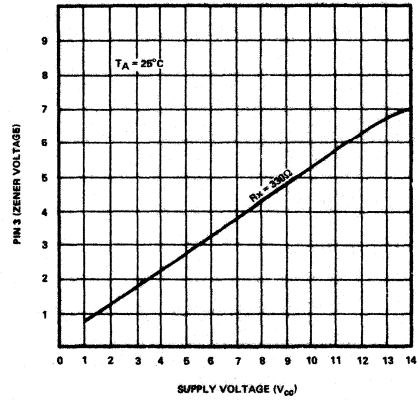
NOTE: Rx is external resistor between pins 3 and V supply.

TYPICAL CHARACTERISTICS (Cont'd)

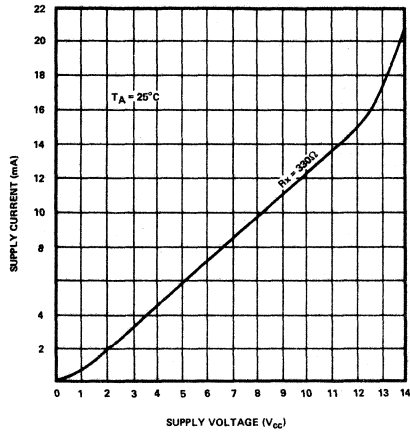
IF CURRENT VERSUS SUPPLY VOLTAGE



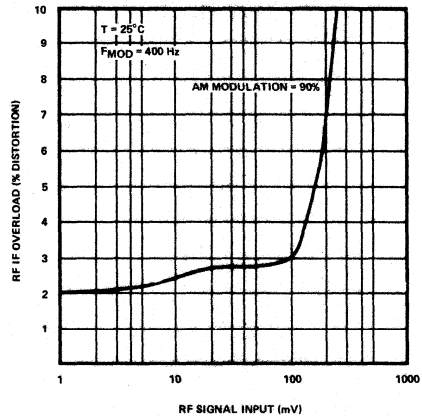
PIN 3 VOLTAGE VERSUS SUPPLY VOLTAGE



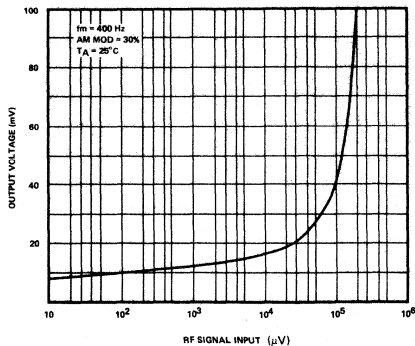
ICC VERSUS Vcc



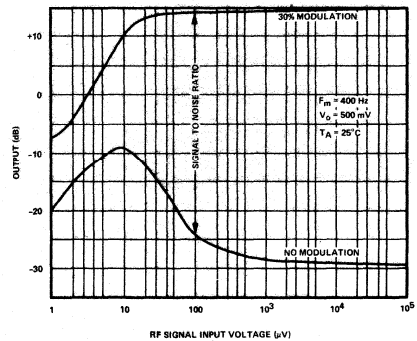
OVERLOAD RESPONSE  
DISTORTION VERSUS RF INPUT



AGC CURVE



SIGNAL TO NOISE RATIO



NOTE:  $R_x$  is external resistor between pins 3 and V supply.

TYPICAL APPLICATIONS

AM RADIO (Capacitor Tuned)

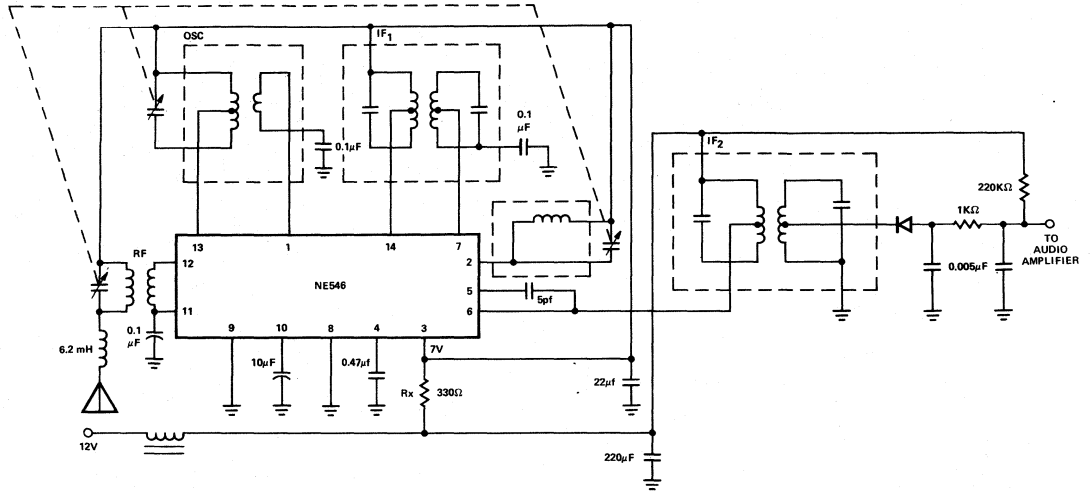


FIGURE 1

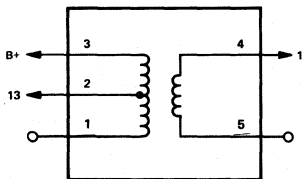
VARIABLE CAPACITOR (Air Varicon)

- ANT & RF 13 pF ~ 190 pF
- OSC 12 pF ~ 80 pF

ANTENNA COIL

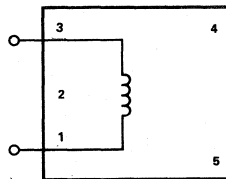
10 mm φ x 120 mm Ferrite Antenna

RF COIL



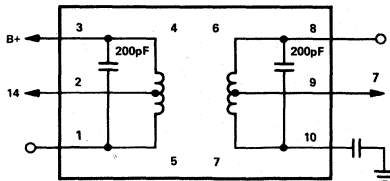
- 1-2 44 Turns
- 2-3 81 Turns
- 4-5 8 Turns

OSC COIL



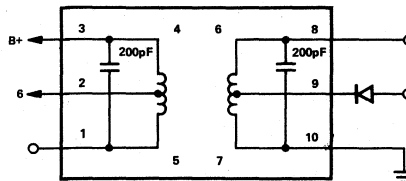
- 1-3 95 Turns

1st. IF COIL



- 1-2 120 Turns
  - 2-3 80 Turns
  - 9-10 15 Turns
  - 9-8 185 Turns
- Core: k = 0.021

2nd. IF COIL

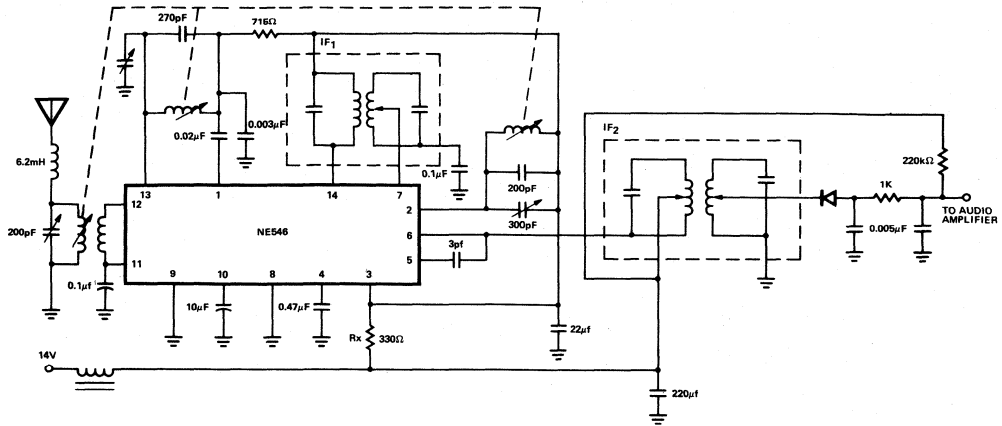


- 1-2 120 Turns
  - 2-3 80 Turns
  - 9-10 30 Turns
  - 9-8 170 Turns
- Core: k = 0.021

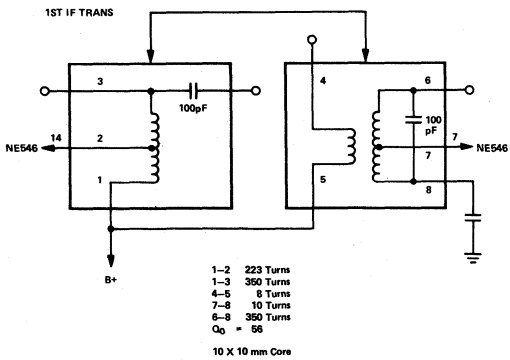
FIG. 1 (Con'd)

AM CAR RADIO (Slug Tuned)

AM CAR RADIO (Slug Tuned)



1st. IF TRANSFORMER



2nd. IF TRANSFORMER

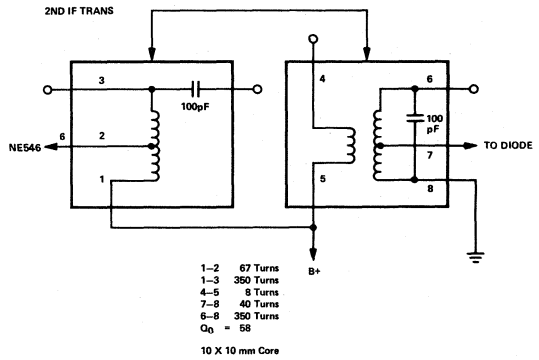
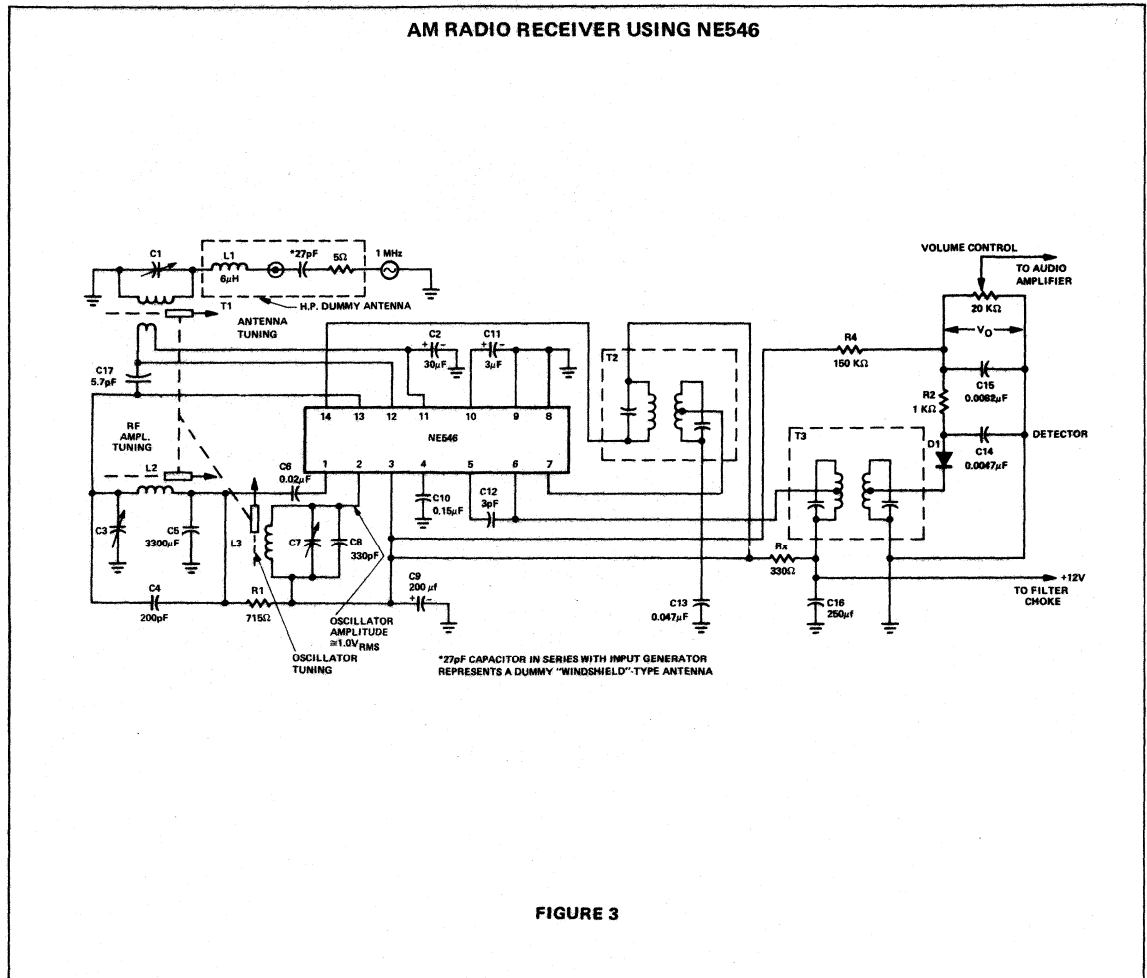


FIGURE 2

SCHEMATIC DIAGRAM



TRANSFORMER	SYMBOL	FREQUENCY	INDUCTANCE μh (≈)	CAPACITANCE pF (≈)	Q (≈)	TOTAL TURNS TO TAP TURNS RATIO
First IF: Primary	T <sub>2</sub>	262.5 kHz	2840	130	60	none or 30:1 31:1
Secondary						
Second IF: Primary	T <sub>3</sub>	262.5 kHz	2840	130	60	8.5:1 8.5:1
Secondary						
Antenna: Primary	T <sub>1</sub>	1 MHz	195	(C <sub>1</sub> )-130	65	Adjusted to an impedance of 75Ω with primary resonant at 1 MHz. Coupling should be as tight as practical. Wire should be wound around end of coil away from tuning core.
Secondary						
Coils	L <sub>1</sub>	7.9 MHz	6		50	
	L <sub>2</sub>	1 MHz	55		50	
	L <sub>2</sub>	1.262 MHz	41		40	



COMPLETE AM RADIO WITH AUDIO DRIVER AND OUTPUT STAGE

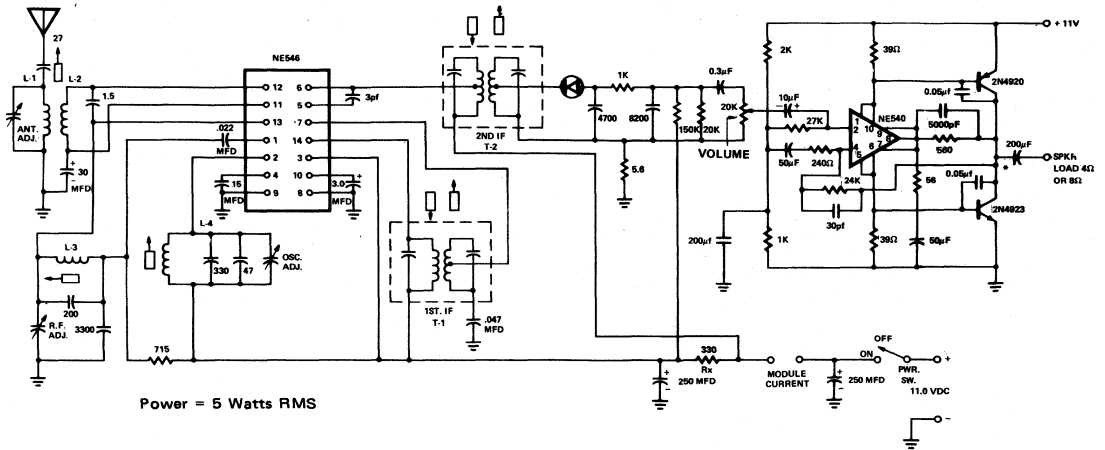


FIGURE 4

## LINEAR INTEGRATED CIRCUITS

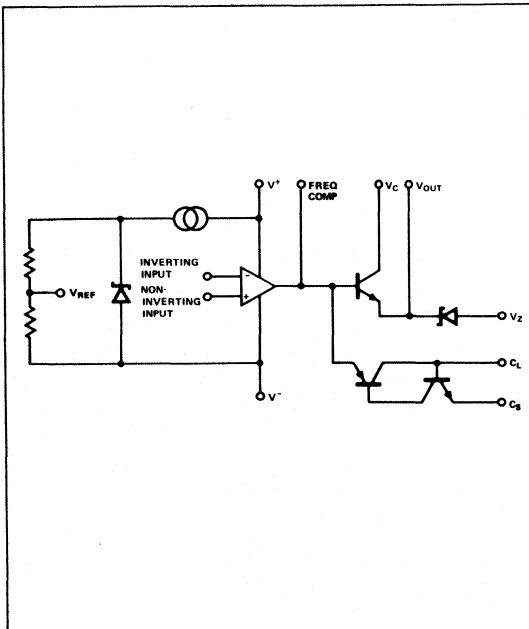
### DESCRIPTION

The 550 is a precision monolithic voltage regulator capable of positive or negative supply operation as series, shunt, switching or floating regulator. Guaranteed line regulation is provided for input voltages ranging from 8.5 volts to as high as 50 volts. The output voltage can be continuously adjusted from 2 volts to 40 volts. Foldback current limiting can be accomplished through the use of one external resistor. Internal circuitry permits on and off strobing with DTL and TTL logic inputs and latched shut-down with a pulsed input.

### FEATURES

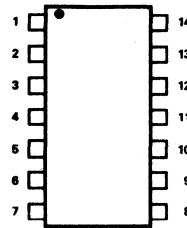
- LINE REGULATION GUARANTEED OVER INPUT VOLTAGE RANGE OF 8.5 VOLTS TO AS HIGH AS 50 VOLTS.
- OUTPUT VOLTAGE CONTINUOUSLY ADJUSTABLE FROM 2 VOLTS TO 40 VOLTS
- .01% LINE AND LOAD REGULATION
- ADJUSTABLE LIMITING OF SHORT CIRCUIT CURRENT
- FOLDBACK CURRENT LIMITING WITH ONE EXTERNAL RESISTOR
- REMOTE AND LATCHING SHUTDOWN
- OUTPUT CURRENT UP TO 150mA WITHOUT EXTERNAL POWER TRANSISTORS

### BASIC CIRCUIT SCHEMATIC



### PIN CONFIGURATIONS (Top View)

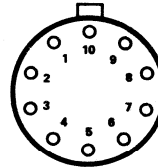
#### A PACKAGE



1. NC
2. Current Limit
3. Current Sense
4. Inverting Input
5. Noninverting Input
6.  $V_{REF}$
7.  $V^-$
8. NC
9.  $V_Z$
10.  $V_{out}$
11.  $V_C$
12.  $V^+$
13. Frequency Compensation
14. NC

ORDER PART NO. NE550A

#### L PACKAGE



1. Current Sense
2. Inverting Input
3. Noninverting Input
4.  $V_{REF}$
5.  $V^-$
6.  $V_{out}$
7.  $V_C$
8.  $V^+$
9. Frequency Compensation
10. Current Limit

ORDER PART NOS. NE550L/SE550L

### ABSOLUTE MAXIMUM RATINGS

	SE550	NE550
Voltage from $V^+$ to $V^-$	50V	40V
Input-Output Voltage		
Differential	45V	37V
Maximum Output Current	150mA	150mA
Current from $V_Z$	15mA	15mA
Internal Power		
Dissipation (Note 1)	800mW	800mW
Operating Temperature		
Range	-55°C to +125°C	-0°C to 70°C
Storage Temperature		
Range	-65°C to +150°C	-65°C to +150°C
Lead Temperature	300°C	300°C

#### NOTE:

1. Rating applies for case temperatures to 125°C; derate linearly at 6.5mW/°C for ambient temperatures above +75°C.

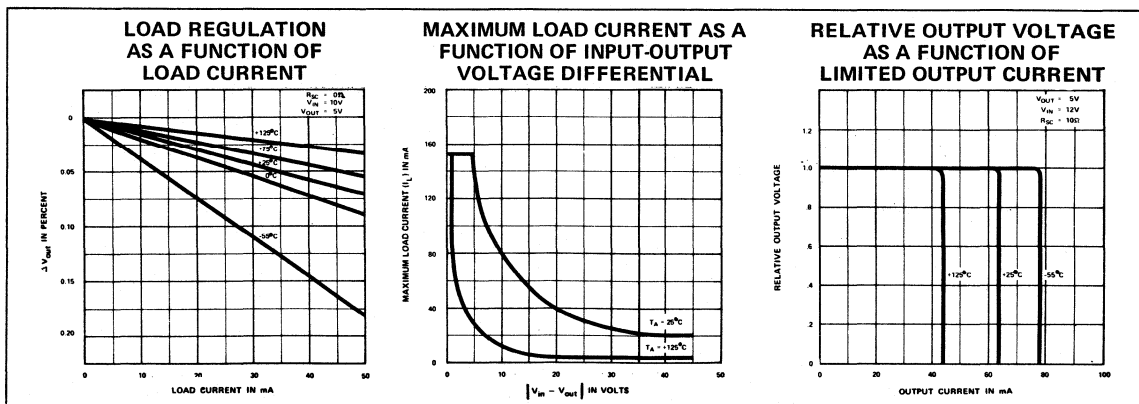
**ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  unless otherwise specified) (Notes 1 and 2)

PARAMETER	MIN	TYP	MAX	UNITS	TEST CONDITIONS
<b>NE550</b>					
Line Regulation		.08	0.3	% $V_{out}$	$V_{in} = 8.5$ to $40\text{V}$ $0^\circ\text{C} \leq T_A \leq 70^\circ\text{C}$ , $V_{in} = 12$ to $40\text{V}$
Load Regulation		.03	0.2	% $V_{out}$	$I_L = 1\text{mA}$ to $50\text{mA}$
Ripple Rejection		75	90	dB	$0^\circ\text{C} \leq T_A \leq 70^\circ\text{C}$ , $I_L = 1\text{mA}$ to $50\text{mA}$
Average Temperature Coefficient of Output Voltage		.002	.015	%/ $^\circ\text{C}$	$0^\circ\text{C} \leq T_A \leq 70^\circ\text{C}$
Short Circuit Current Limit	50	60	70	mA	$R_{SC} = 10\Omega$ , $V_{out} = 0$
Reference Voltage	1.53	1.63	1.73	V	
Output Noise Voltage		20	2.5	$\mu\text{V rms}$	$\text{BW} = 100\text{ Hz to } 10\text{ kHz}$ , $\text{CREF} = 0$
Long Term Stability		0.1		%/1000 hrs.	$\text{BW} = 100\text{ Hz to } 10\text{ kHz}$ , $\text{CREF} = 5\mu\text{F}$
Standby Current Drain		1.6	3.0	mA	$I_L = 0$ , $V_{in} = 40\text{V}$
Input Voltage Range	8.5		40	V	
Output Voltage Range	2.0		37	V	
Input-Output Voltage Differential	3.0		38	V	
<b>SE550</b>					
Line Regulation		0.05	0.1	% $V_{out}$	$V_{in} = 12$ to $40\text{V}$
Load Regulation		0.2	0.6	% $V_{out}$	$V_{in} = 8.5$ to $50\text{V}$
Ripple Rejection		75	90	dB	$-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$ , $V_{in} = 12$ to $40\text{V}$
Average Temperature Coefficient of Output Voltage		.002	.012	%/ $^\circ\text{C}$	$-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$
Short Circuit Limit	50	60	70	mA	$R_{SC} = 10\Omega$ , $V_{out} = 0$
Reference Voltage	1.58	1.63	1.68	V	
Output Noise Voltage		20	2.5	$\mu\text{V rms}$	$\text{BW} = 100\text{ Hz to } 10\text{ kHz}$ , $\text{CREF} = 0$
Long Term Stability		0.1		%/1000 hrs.	$\text{BW} = 100\text{ Hz to } 10\text{ kHz}$ , $\text{CREF} = 5\mu\text{F}$
Standby Current Drain		1.3	2.0	mA	$I_L = 0$ , $V_{in} = 50\text{V}$
Input Voltage Range	8.5		50	V	
Output Voltage Range	2.0		40	V	
Input-Output Voltage Differential	3.0		45	V	

**NOTES**

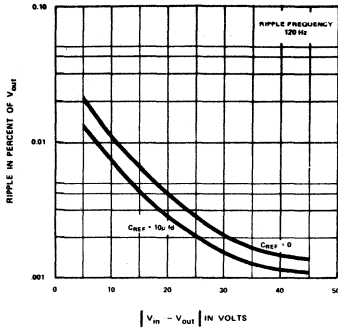
1. Unless otherwise specified,  $T_A = 25^\circ\text{C}$ ,  $V_{in} = V^+ = V_c = 12\text{V}$ ,  $V^- = 0\text{V}$ ,  $V_{out} = 5\text{V}$ ,  $I_L = 1\text{mA}$ ,  $R_{sc} = 0$ ,  $C_1 = 100\mu\text{F}$ , and divider impedance as seen by error amplifier  $\approx 2\text{k}\Omega$  when connected as shown in Figure 1.
2. The load and line regulation specifications are for constant junction temperature. Temperature drift effects must be taken into account separately when the unit is operating under conditions of high or varying dissipation.

**TYPICAL CHARACTERISTIC CURVES**

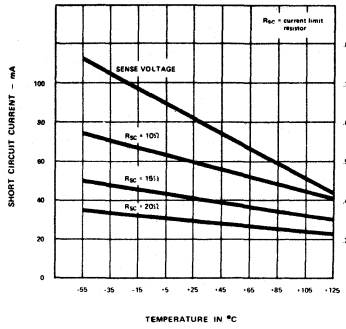


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

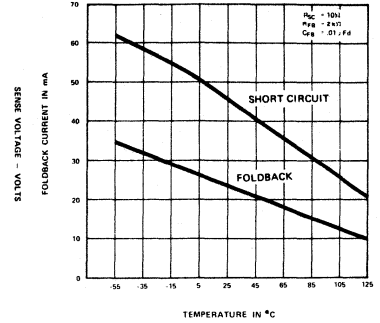
**RIPPLE REJECTION AS A FUNCTION OF INPUT-OUTPUT VOLTAGE DIFFERENTIAL**



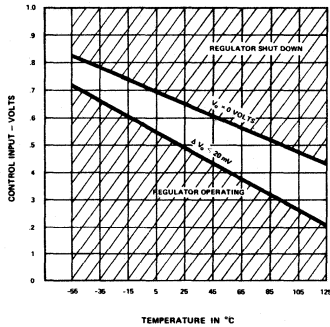
**SENSE VOLTAGE AND SHORT CIRCUIT CURRENT LIMIT AS A FUNCTION OF TEMPERATURE**



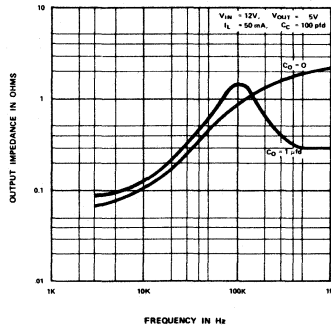
**SHORT CIRCUIT AND FOLDBACK CURRENTS AS A FUNCTION OF TEMPERATURE**



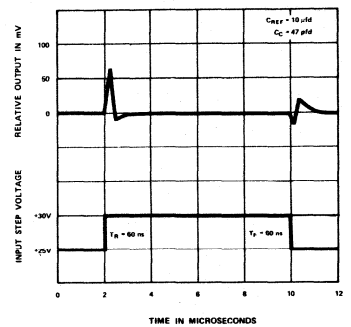
**REMOTE CONTROL CHARACTERISTICS AS A FUNCTION OF TEMPERATURE**



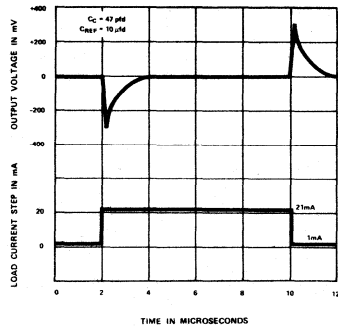
**OUTPUT IMPEDANCE AS A FUNCTION OF FREQUENCY**



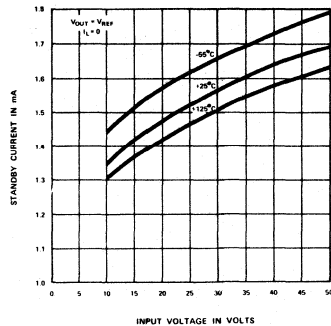
**LINE TRANSIENT RESPONSE**



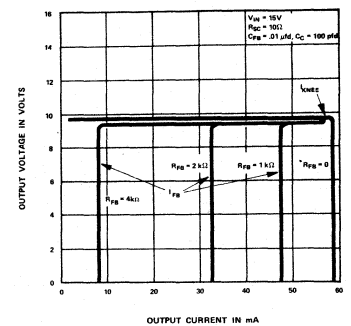
**LOAD TRANSIENT RESPONSE**



**STANDBY CURRENT AS A FUNCTION OF INPUT VOLTAGE**



**FOLDBACK CURRENT LIMITED OUTPUT VOLTAGE AS A FUNCTION OF OUTPUT CURRENT**



TYPICAL APPLICATIONS

**BASIC POSITIVE VOLTAGE REGULATOR**

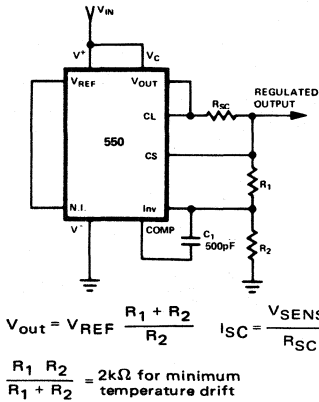


FIGURE 1

**NEGATIVE VOLTAGE REGULATOR**

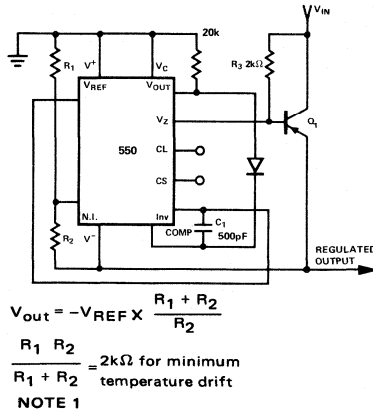


FIGURE 2

**POSITIVE VOLTAGE REGULATOR (External PNP Pass Transistor)**

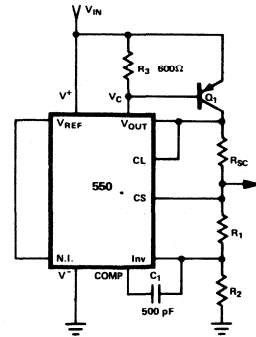


FIGURE 3

**POSITIVE VOLTAGE REGULATOR (External NPN Pass Transistor)**

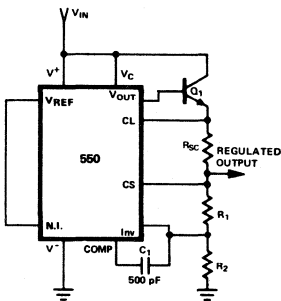


FIGURE 4.

**FOLDBACK CURRENT LIMITED REGULATOR**

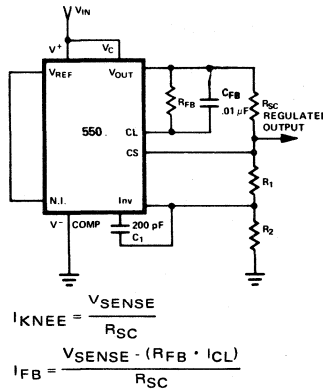


FIGURE 5A

**SECOND ORDER FOLDBACK CURRENT LIMITED REGULATOR**

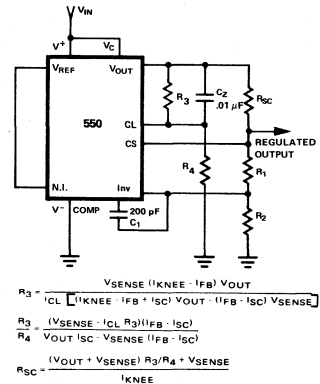
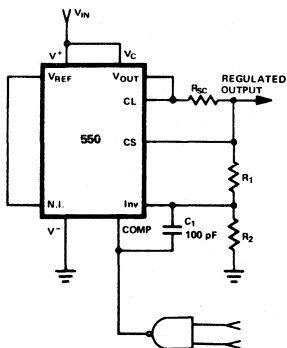


FIGURE 5B

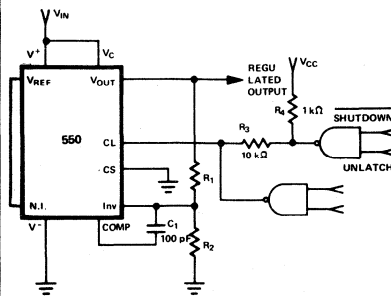
**REMOTE SHUTDOWN REGULATOR WITH CURRENT LIMITING**



1/4 8T80, 1/6 8T90, 1/10 8T01B, etc.

FIGURE 6

**REMOTE LATCHING SHUTDOWN REGULATOR**

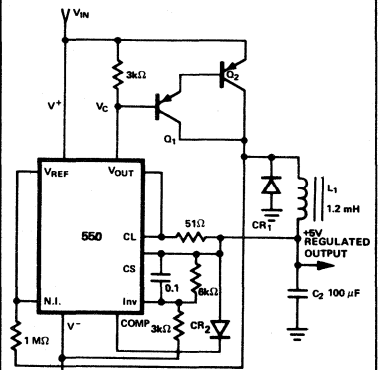


8415, 8417, 2/3 8471, 1/3 8891, 8T90, 1/2 8481, 8881, 8T90

NOTE 2

FIGURE 7

**POSITIVE SWITCHING REGULATOR**



L1 is 50 turns of #22 wire wound on Ferroxcube. 42/29-377 A400

FIGURE 8

TYPICAL APPLICATIONS (Cont'd.)

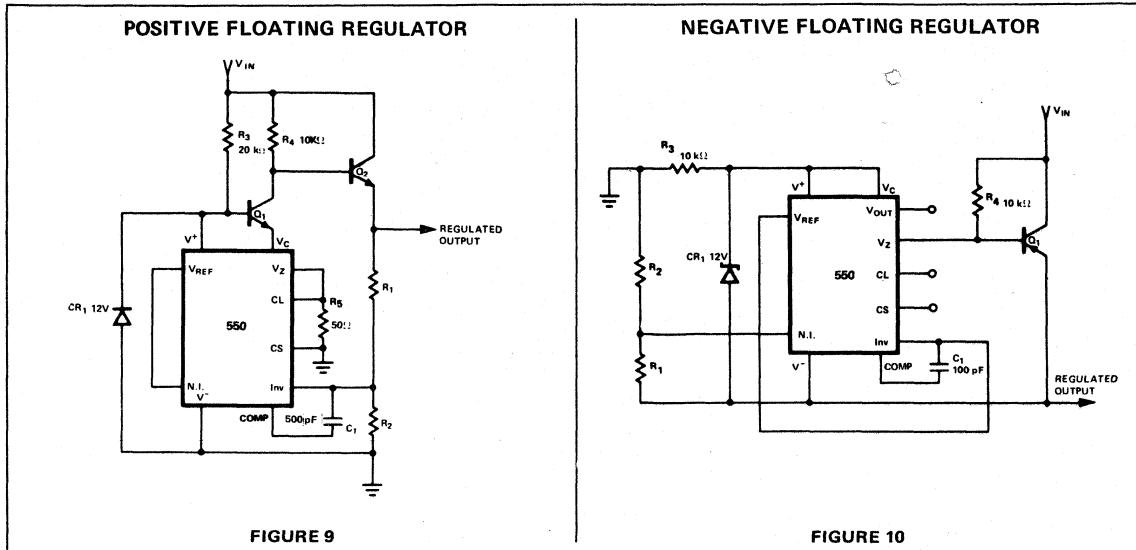


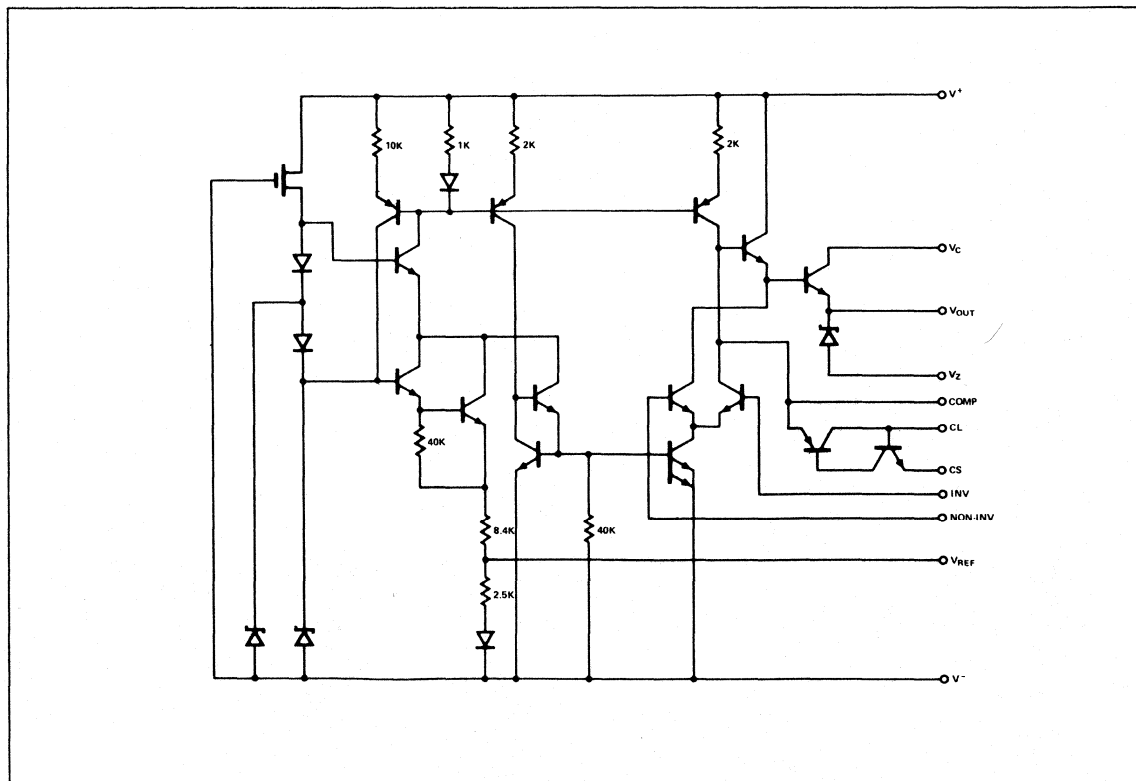
FIGURE 9

FIGURE 10

NOTES:

1. To utilize the SE550L in applications which require  $V_z$ , an external 6.2 volt zener diode should be connected in series with  $V_{OUT}$ .
2. The "Shut-down" gate need only be pulsed to latch the regulator output to zero.  $R_4$  may be omitted for active pull-up devices. The "Unlatch" gate must have an open collector.

EQUIVALENT CIRCUIT



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE/SE 555 monolithic timing circuit is a highly stable controller capable of producing accurate time delays, or oscillation. Additional terminals are provided for triggering or resetting if desired. In the time delay mode of operation, the time is precisely controlled by one external resistor and capacitor. For a stable operation as an oscillator, the free running frequency and the duty cycle are both accurately controlled with two external resistors and one capacitor. The circuit may be triggered and reset on falling waveforms, and the output structure can source or sink up to 200mA or drive TTL circuits.

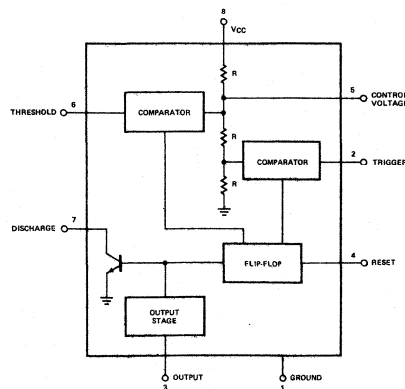
### FEATURES

- TIMING FROM MICROSECONDS THROUGH HOURS
- OPERATES IN BOTH ASTABLE AND MONOSTABLE MODES
- ADJUSTABLE DUTY CYCLE
- HIGH CURRENT OUTPUT CAN SOURCE OR SINK 200mA
- OUTPUT CAN DRIVE TTL
- TEMPERATURE STABILITY OF 0.005% PER °C
- NORMALLY ON AND NORMALLY OFF OUTPUT

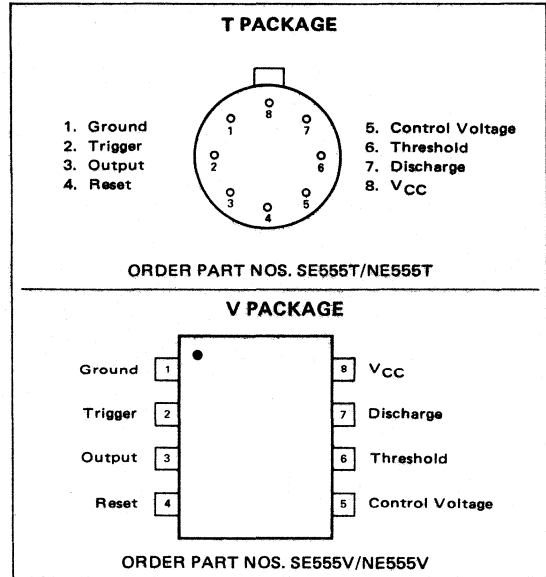
### APPLICATIONS

- PRECISION TIMING
- PULSE GENERATION
- SEQUENTIAL TIMING
- TIME DELAY GENERATION
- PULSE WIDTH MODULATION
- PULSE POSITION MODULATION
- MISSING PULSE DETECTOR

### BLOCK DIAGRAM



### PIN CONFIGURATIONS (Top View)



### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	+18V
Power Dissipation	600 mW
Operating Temperature Range	
NE555	0°C to +70°C
SE555	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering, 60 seconds)	+300°C

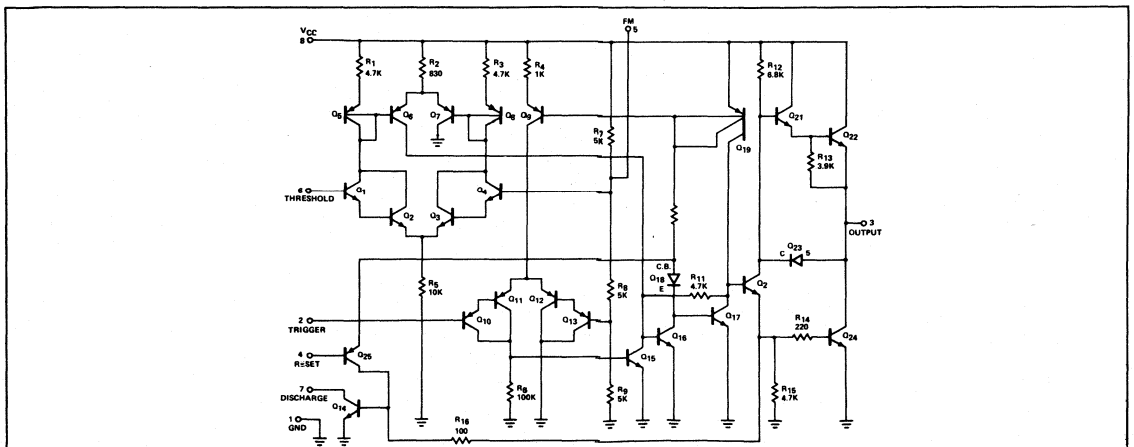
ELECTRICAL CHARACTERISTICS  $T_A = 25^{\circ}\text{C}$ ,  $V_{CC} = +5\text{V}$  to  $+15$  unless otherwise specified

PARAMETER	TEST CONDITIONS	SE 555			NE 555			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Supply Voltage		4.5		18	4.5		16	V
Supply Current	$V_{CC} = 5\text{V}$ $R_L = \infty$		3	5		3	6	mA
	$V_{CC} = 15\text{V}$ $R_L = \infty$		10	12		10	15	mA
Timing Error (Monostable)	Low State, Note 1 $R_A, R_B = 1\text{K}\Omega$ to $100\text{K}\Omega$ $C = 0.1\ \mu\text{F}$ Note 2							
Initial Accuracy			0.5	2		1		%
Drift with Temperature			30	100		50		ppm/ $^{\circ}\text{C}$
Drift with Supply Voltage			0.05	0.2		0.1		%/Volt
Threshold Voltage			2/3			2/3		$\times V_{CC}$
Trigger Voltage	$V_{CC} = 15\text{V}$	4.8	5	5.2		5		V
Timing Error (Astable)	$V_{CC} = 5\text{V}$	1.45	1.67	1.9		1.67		V
Trigger Current			0.5			0.5		$\mu\text{A}$
Reset Voltage		0.4	0.7	1.0	0.4	0.7	1.0	V
Reset Current			0.1			0.1		mA
Threshold Current	Note 3		0.1	.25		0.1	.25	$\mu\text{A}$
Control Voltage Level	$V_{CC} = 15\text{V}$	9.6	10	10.4	9.0	10	11	V
	$V_{CC} = 5\text{V}$	2.9	3.33	3.8	2.6	3.33	4	V
Output Voltage (low)	$V_{CC} = 15\text{V}$ $I_{\text{SINK}} = 10\text{mA}$		0.1	0.15		0.1	.25	V
	$I_{\text{SINK}} = 50\text{mA}$		0.4	0.5		0.4	.75	V
	$I_{\text{SINK}} = 100\text{mA}$		2.0	2.2		2.0	2.5	V
	$I_{\text{SINK}} = 200\text{mA}$		2.5			2.5		V
	$V_{CC} = 5\text{V}$ $I_{\text{SINK}} = 8\text{mA}$		0.1	0.25				V
	$I_{\text{SINK}} = 5\text{mA}$					.25	.35	V
Output Voltage Drop (low)	$I_{\text{SOURCE}} = 200\text{mA}$ $V_{CC} = 15\text{V}$		12.5			12.5		V
	$I_{\text{SOURCE}} = 100\text{mA}$ $V_{CC} = 15\text{V}$	13.0	13.3		12.75	13.3		V
	$V_{CC} = 5\text{V}$	3.0	3.3		2.75	3.3		V
Rise Time of Output			100			100		nsec
Fall Time of Output			100			100		nsec

NOTES

- Supply Current when output high typically 1mA less.
- Tested at  $V_{CC} = 5\text{V}$  and  $V_{CC} = 15\text{V}$
- This will determine the maximum value of  $R_A + R_B$ . For 15V operation, the max total R = 20 megohm.

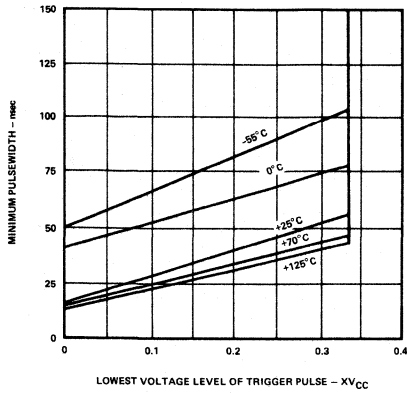
EQUIVALENT CIRCUIT (Shown for One Side Only)



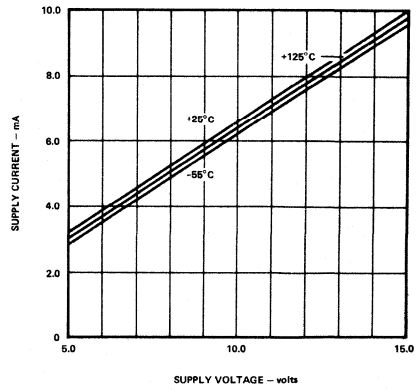


TYPICAL CHARACTERISTICS

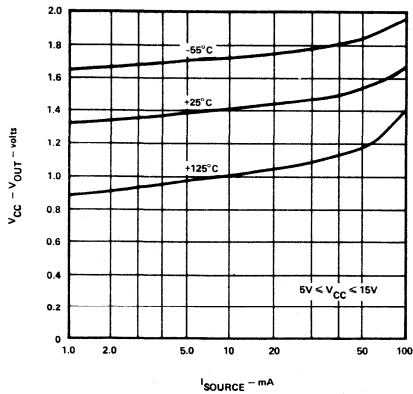
MINIMUM PULSE WIDTH  
REQUIRED FOR TRIGGERING



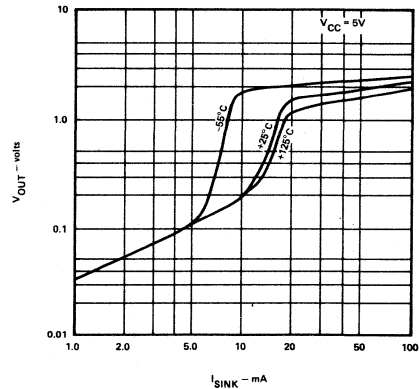
SUPPLY CURRENT  
vs SUPPLY VOLTAGE



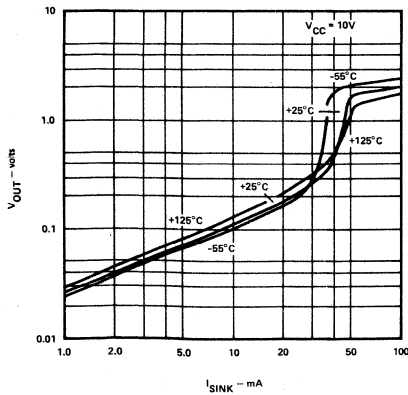
LOW OUTPUT VOLTAGE  
vs OUTPUT SINK CURRENT



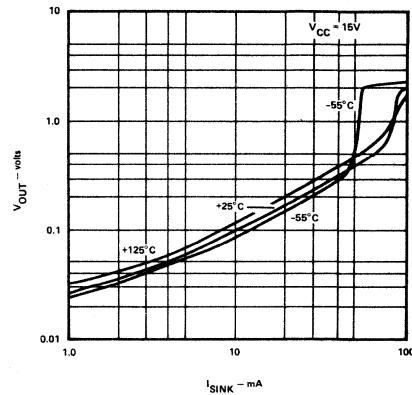
HIGH OUTPUT VOLTAGE  
vs OUTPUT  
SOURCE CURRENT



LOW OUTPUT VOLTAGE  
vs OUTPUT SINK CURRENT

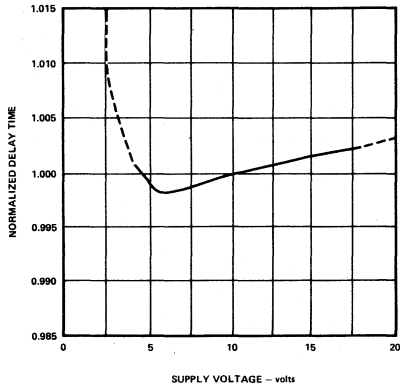


LOW OUTPUT VOLTAGE  
vs OUTPUT SINK CURRENT

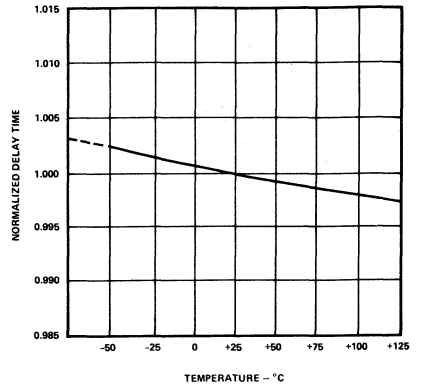


TYPICAL CHARACTERISTICS (Cont'd)

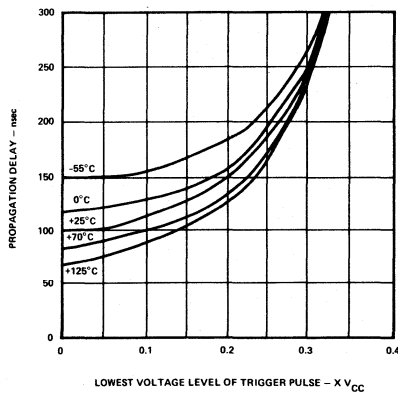
**DELAY TIME vs SUPPLY VOLTAGE**



**DELAY TIME vs TEMPERATURE**



**PROPAGATION DELAY vs VOLTAGE LEVEL OF TRIGGER PULSE**



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE/SE556 Dual Monolithic timing circuit is a highly stable controller capable of producing accurate time delays or oscillation. The 556 is a dual 555. Timing is provided by an external resistor and capacitor for each timing function. The two timers operate independently of each other sharing only  $V_{CC}$  and ground. The circuits may be triggered and reset on falling waveforms. The output structures may sink or source 150mA.

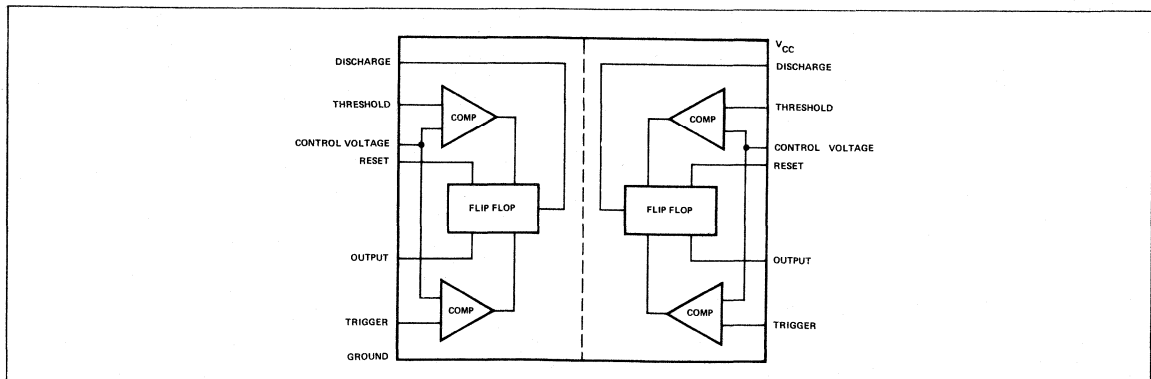
### FEATURES

- TIMING FROM MICROSECONDS TO HOURS
- REPLACES TWO 555 TIMERS
- OPERATES IN BOTH ASTABLE, MONOSTABLE, TIME DELAY MODES
- HIGH OUTPUT CURRENT
- ADJUSTABLE DUTY CYCLE
- TTL COMPATIBLE
- TEMPERATURE STABILITY OF 0.005% PER °C

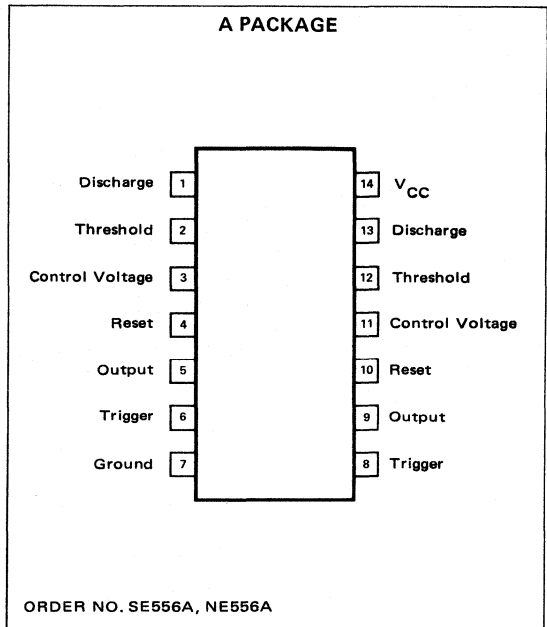
### APPLICATIONS

- PRECISION TIMING
- SEQUENTIAL TIMING
- PULSE SHAPING
- PULSE GENERATOR
- MISSING PULSE DETECTOR
- TONE BURST GENERATOR
- PULSE WIDTH MODULATION
- TIME DELAY GENERATOR
- FREQUENCY DIVISION
- INDUSTRIAL CONTROLS
- PULSE POSITION MODULATION
- APPLIANCE TIMING
- TRAFFIC LIGHT CONTROL
- TOUCH TONE ENCODER

### BLOCK DIAGRAM



### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS

Supply Voltage		+18V
Power Dissipation		600mW
Operating Temperature Range	NE556	0°C to +70°C
	SE556	-55°C to +125°C
	SE556C	-55°C to +125°C
Storage Temperature Range		-65°C to +150°C
Lead Temperature (Soldering, 60 sec)		+300°C

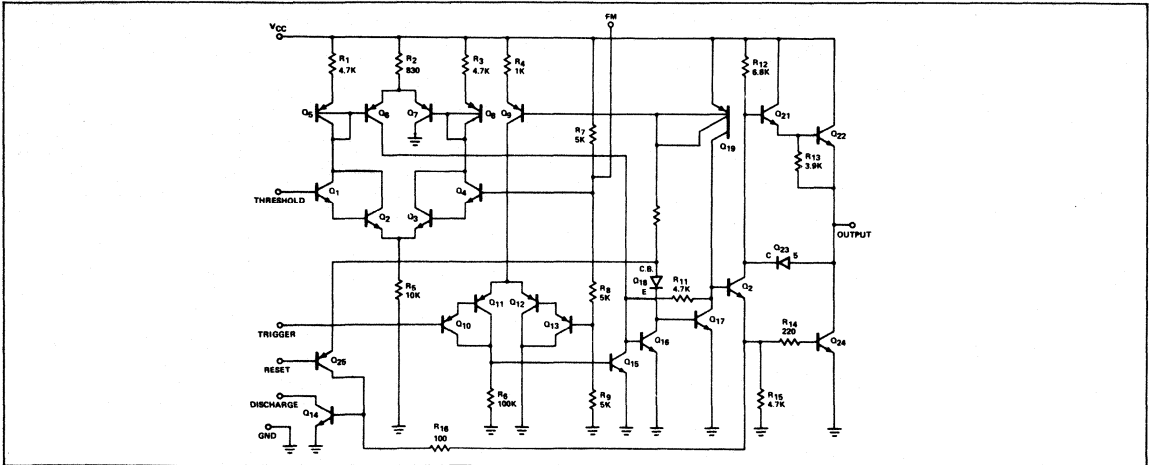
ELECTRICAL CHARACTERISTICS  $T_A = 25^\circ\text{C}$ ,  $V_{CC} = +5\text{V}$  to  $+15$  unless otherwise specified

PARAMETER	TEST CONDITIONS	SE 556			NE 556			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Supply Voltage		4.5		18	4.5		16	V
Supply Current	$V_{CC} = 5\text{V}$ $R_L = \infty$ $V_{CC} = 15\text{V}$ $R_L = \infty$ Low State, Note 1		3	5		3	6	mA
			10	11		10	14	mA
Timing Error (Monostable)	$R_A = 2\text{K}\Omega$ to $100\text{K}\Omega$ $C = 0.1\mu\text{F}$ Note 2							
Initial Accuracy			0.5	1.5		0.75		%
Drift with Temperature			30	100		50		ppm/ $^\circ\text{C}$
Drift with Supply Voltage			0.05	0.2		0.1		%/Volt
Timing Error (Astable)	$R_A, R_B = 2\text{K}\Omega$ to $100\text{K}\Omega$ $C = 0.1\mu\text{F}$ Note 2							
Initial Accuracy			1.5			2.25		%
Drift with Temperature			90			150		ppm/ $^\circ\text{C}$
Drift with Supply Voltage			0.15			0.3		%/Volt
Threshold Voltage			2/3			2/3		$\times V_{CC}$
Threshold Current	Note 3		30	100		30	100	nA
Trigger Voltage	$V_{CC} = 15\text{V}$ $V_{CC} = 5\text{V}$	4.8	5	5.2		5		V
		1.45	1.67	1.9		1.67		V
Trigger Current			0.5			0.5		$\mu\text{A}$
Reset Voltage		0.4	0.7	1.0	0.4	0.7	1.0	V
Reset Current			0.1			0.1		mA
Control Voltage Level	$V_{CC} = 15\text{V}$ $V_{CC} = 5\text{V}$	9.6	10	10.4	9.0	10	11	V
		2.9	3.33	3.8	2.6	3.33	4	V
Output Voltage (low)	$V_{CC} = 15\text{V}$ $I_{\text{SINK}} = 10\text{mA}$ $I_{\text{SINK}} = 50\text{mA}$ $I_{\text{SINK}} = 100\text{mA}$ $I_{\text{SINK}} = 200\text{mA}$ $V_{CC} = 5\text{V}$ $I_{\text{SINK}} = 8\text{mA}$ $I_{\text{SINK}} = 5\text{mA}$		0.1	0.15		0.1	.25	V
			0.4	0.5		0.4	.75	V
			2.0	2.25		2.0	2.75	V
			2.5			2.5		V
			0.1	0.25				V
						.25	.35	V
Output Voltage (high)	$I_{\text{SOURCE}} = 200\text{mA}$ $V_{CC} = 15\text{V}$ $I_{\text{SOURCE}} = 100\text{mA}$ $V_{CC} = 15\text{V}$ $V_{CC} = 5\text{V}$		12.5			12.5		V
		13.0	13.3		12.75	13.3		V
		3.0	3.3		2.75	3.3		V
Rise Time of Output			100			100		nsec
Fall Time of Output			100			100		nsec
Discharge Leakage Current			20	100		20	100	nA
Matching Characteristics (Note 4)								
Initial Timing Accuracy			0.05	0.1		0.1	0.2	%
Timing Drift with Temperature			$\pm 10$			$\pm 10$		ppm/ $^\circ\text{C}$
Drift with Supply Voltage			0.1	0.2		0.2	0.5	%/Volt

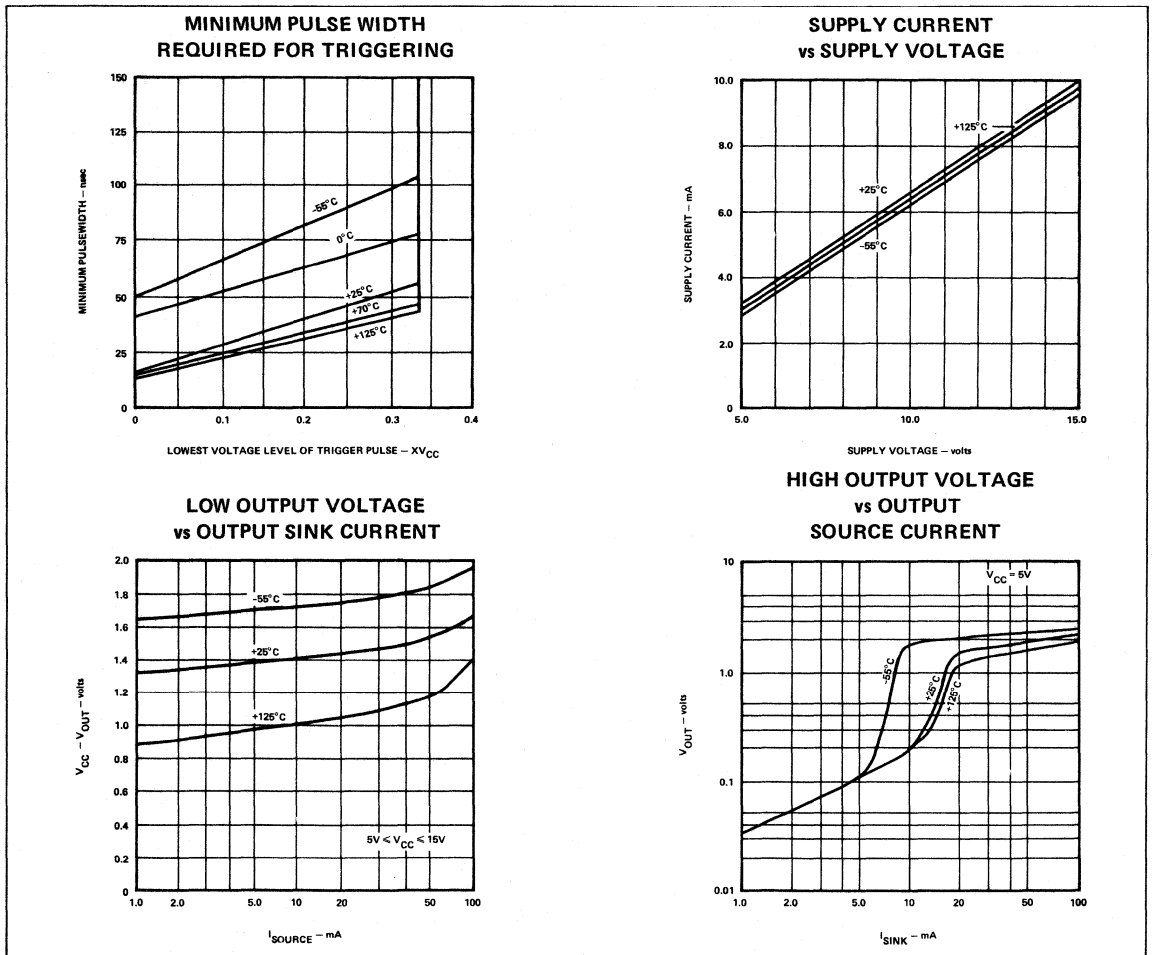
NOTES

1. Supply current when output is high is typically 1.0ma less.
2. Tested at  $V_{CC} = 5\text{V}$  and  $V_{CC} = 15\text{V}$ .
3. This will determine the maximum value of  $R_A + R_B$  for 15V operation. The maximum total R = 20 meg-ohms.
4. Matching characteristics refer to the difference between performance characteristics of each timer section.

EQUIVALENT CIRCUIT (Shown for One Side Only)

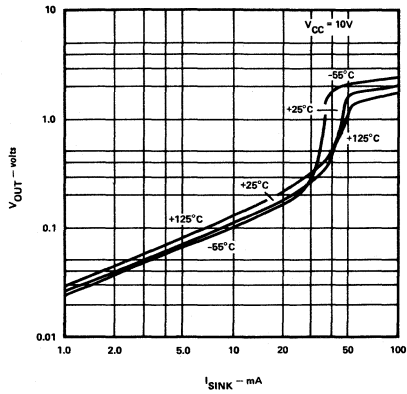


TYPICAL CHARACTERISTICS

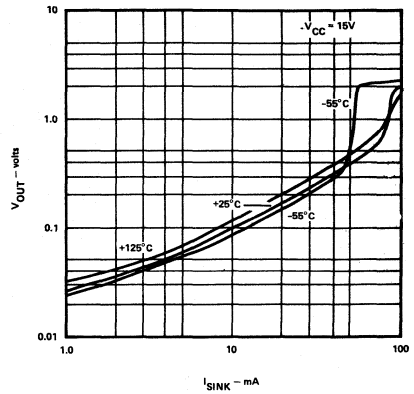


TYPICAL CHARACTERISTICS (Cont'd)

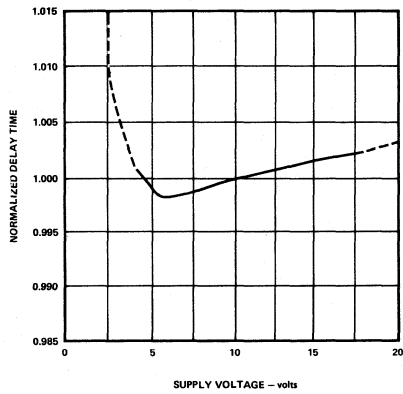
LOW OUTPUT VOLTAGE vs OUTPUT SINK CURRENT



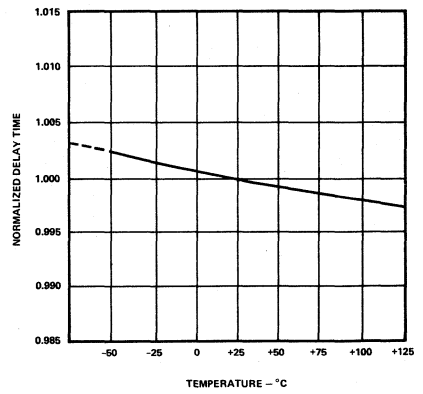
LOW OUTPUT VOLTAGE vs OUTPUT SINK CURRENT



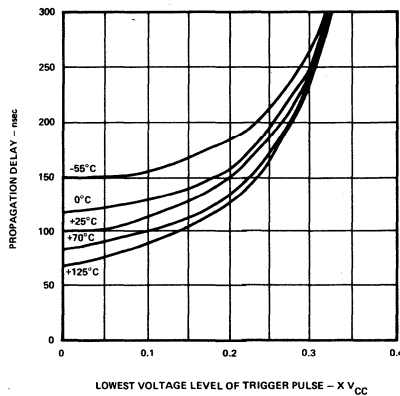
DELAY TIME vs SUPPLY VOLTAGE



DELAY TIME vs TEMPERATURE



PROPAGATION DELAY vs VOLTAGE LEVEL OF TRIGGER PULSE



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE560B Phase Locked Loop (PLL) is a monolithic signal conditioner, and demodulator system comprising a VCO, Phase Comparator, Amplifier and Low Pass Filter, interconnected as shown in the accompanying block diagram. The center frequency of the PLL is determined by the free running frequency ( $f_0$ ) of the VCO. This VCO frequency is set by an external capacitor and can be fine tuned by an optional Potentiometer. The low pass filter, which determines the capture characteristics of the loop, is formed by the two capacitors and two resistors at the Phase Comparator output.

The PLL system has a set of self biased inputs which can be utilized in either a differential or single ended mode. The VCO output, in differential form, is available for signal conditioning frequency synchronization, multiplication and division applications. Terminals are provided for optional extended control of the tracking range, VCO frequency, and output DC level.

The monolithic signal conditioner-demodulator system is useful over a wide range of frequencies from less than 1 Hz to more than 15 MHz with an adjustable tracking range of  $\pm 1\%$  to  $\pm 15\%$ .

### FEATURES

- FM DEMODULATION WITHOUT TUNED CIRCUITS
- NARROW BANDPASS - TO  $\pm 1\%$  ADJUSTABLE
- TRACKING RANGE
- EXACT FREQUENCY DUPLICATION IN HIGH
- NOISE ENVIRONMENT
- WIDE TRACKING RANGE  $\pm 15\%$
- HIGH LINEARITY - 1% DISTORTION MAX
- FREQUENCY MULTIPLICATION AND DIVISION
- THROUGH HARMONIC LOCKING

### APPLICATIONS

TONE DECODERS

FM IF STRIPS

TELEMETRY DECODERS

DATA SYNCHRONIZERS

SIGNAL RECONSTITUTION

SIGNAL GENERATORS

MODEMS

TRACKING FILTERS

SCA RECEIVERS

FSK RECEIVERS

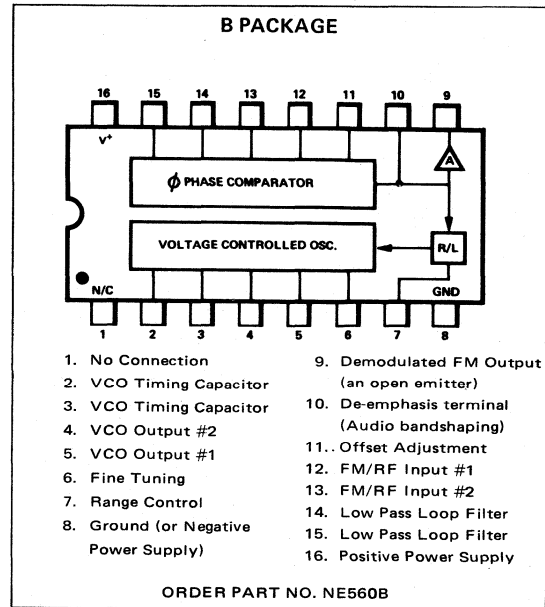
WIDE BAND HIGH LINEARITY DETECTORS

### ABSOLUTE MAXIMUM RATINGS

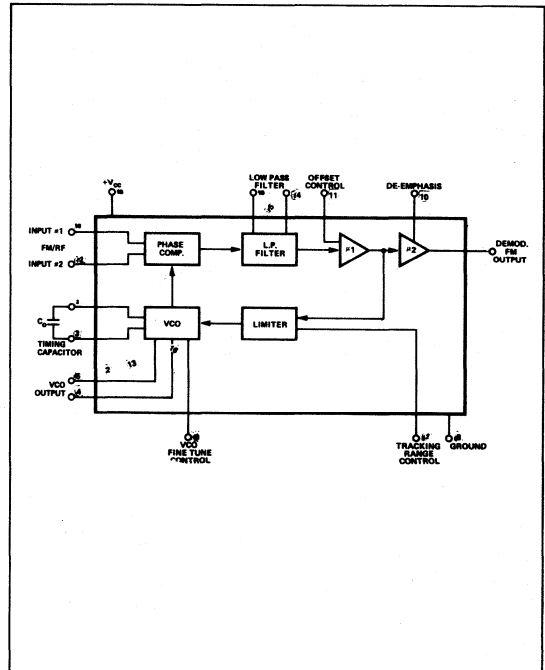
Maximum Operating Voltage	26V
Input Voltage	1V Rms
Storage Temperature	-65°C to 150°C
Operating Temperature	0°C to 70°C
Power Dissipation	300 mw

Limiting values above which serviceability may be impaired

### PIN CONFIGURATION (Top View)



### BLOCK DIAGRAM



**GENERAL ELECTRICAL CHARACTERISTICS**

(15KΩ Pin 9 to GND, Input Pin 12 or Pin 13 AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
Lowest Practical Operating Frequency		0.1		Hz	Measured at 2 MHz, with both inputs AC grounded
Maximum Operating Frequency	15	30		MHz	
Supply Current	7	9	11	Ma	
Minimum Input Signal for Lock		100		μV	
Dynamic Range		60		dB	
VCO Temp Coefficient*		±0.06	±0.12	%/°C	
VCO Supply Voltage Regulation		±0.3	±2	%/V	
Input Resistance		2		KΩ	
Input Capacitance		4		Pf	
Input DC Level		+4		V	
Output DC Level	+12	+14	+16	V	Measured at Pin 9 See Figure 1
Available Output Swing		4		V <sub>p-p</sub>	
AM Rejection*	30	40		dB	
De-emphasis Resistance		8		KΩ	

\*ACC Test Sub Group C.

**ELECTRICAL CHARACTERISTICS (For FM Applications, Figure 2)** (15KΩ Pin 9 to GND, Input Pin 12 or 13, AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
<b>10.7 MHz Operation</b> Deviation 75 kHz Source Impedance = 50Ω					
Detection Threshold	30	120	300	μV	V <sub>in</sub> = 1 mv Rms Modulation Frequency 1 kHz V <sub>in</sub> = 1 mv Rms Modulation Frequency 1 kHz V <sub>in</sub> = 1 mv Rms Modulation Frequency 1 kHz
Demodulated Output Amplitude		60		mV	
Distortion*		.3	1	% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		35		dB	
<b>4.5 MHz Operation</b> Deviation = 25 kHz, Source Impedance = 50Ω					
Detection Threshold	30	120	300	μV	V <sub>in</sub> = 1 mv Rms Modulation Frequency 1 kHz V <sub>in</sub> = 1 mv Rms Modulation Frequency 1 kHz V <sub>in</sub> = 1 mv Rms Modulation Frequency 1 kHz
Demodulated Output Amplitude		60		mV	
Distortion		0.3	1.0	% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		35		dB	
<b>Wide Deviation</b> ΔF/f <sub>o</sub> = 5% Input = 4.5 MHz Deviation = 225 kHz @ 1 kHz Modulation Rate					
Detection Threshold	0.2	1	5	mV	V <sub>in</sub> = 5 mv Rms V <sub>in</sub> = 5 mv Rms V <sub>in</sub> = 5 mv Rms
Demodulated Output		0.5		V <sub>rms</sub>	
Distortion		0.8		% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		50		dB	

\*ACC Test Sub Group C.

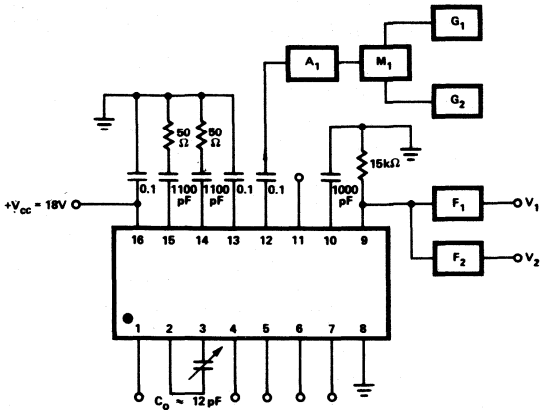
**ELECTRICAL CHARACTERISTICS (For Tracking Filter, Figure 3)** (15KΩ Pin 9 to GND, Input Pin 12 or Pin 13 AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
Tracking Range	±5	±15		% of f <sub>o</sub>	V <sub>in</sub> = 5 mv Rms Input 2 MHz - See Characteristic Curves
Minimum Signal to Sustain Lock 0°C to 70°C		0.8		mv Rms	
VCO Output Impedance		1		kΩ	Input 2 MHz Measured with high impedance Probe with less than 10 Pf Capacitance
VCO Output Swing	0.4	0.6		V <sub>p-p</sub>	
VCO Output DC Level		+6.5		V	Input 2 MHz with ±100 kHz Side Band Separation and 3 kHz Low Pass Filter Input 1 mv Peak for Carrier Each Side Band C <sub>1</sub> = 0.01 μF R <sub>1</sub> = 0
Side Band Suppression		35		dB	



TYPICAL TEST CIRCUITS

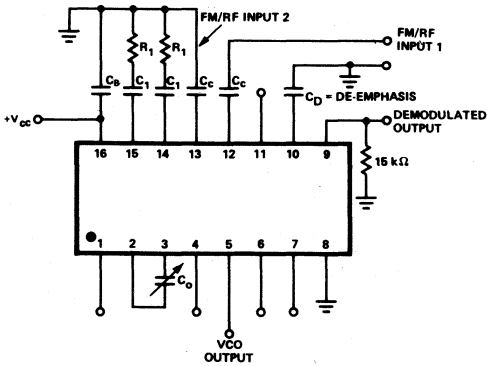
AM REJECTION



- $G_1$  = FM Generator with  $f_c = f_o \approx 4$  MHz  
 $\Delta f = 40$  kHz,  
 $f_{mod} = 1$  kHz
- $G_2$  = Audio Generator with  $f_A = 400$  Hz
- $M_1$  = Balanced Modulator Carrier Supplied by  $G_1$ , AM modulation provided by  $G_2$ .
- $A_1$  =  $50 \Omega$  attenuator pad with signal level into pin 12 adjusted to 1 mV rms.
- $F_1$  = 1 kHz Bandpass filter,  $Q = 20$
- $F_2$  = 400 Hz Bandpass filter with  $Q = 50$ , with 1 kHz trap.
- $AMR = \frac{V_1}{V_2}$  in dB
- $V_1$  and  $V_2$  are rms voltmeter readings.

Fig. 1

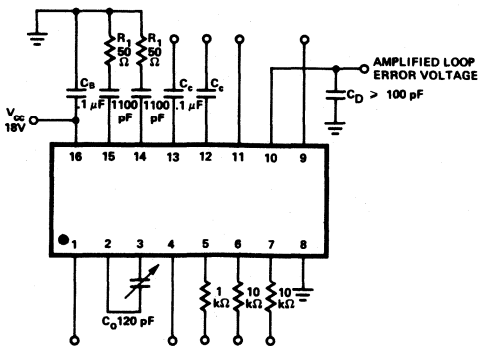
FM DEMODULATION



- $C_B$  = Bypass Capacitor
- $C_C$  = Coupling Capacitors
- $C_1$  = Low Pass Filter Capacitors
- $C_0$  = Frequency Determining Capacitor
- $T_D$  = De-emphasis time constant  
 $= (C_D) (8k\Omega)$

Fig. 2

TRACKING FILTER

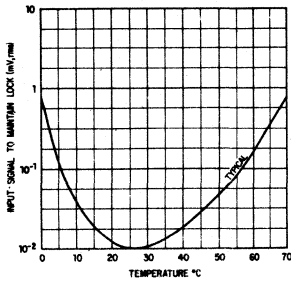


- $C_C$  = Coupling Capacitors
- $C_B$  = Bypass Capacitor
- $C_1$  = Low Pass Filter Capacitor
- $C_0$  = VCO Frequency Set Capacitor

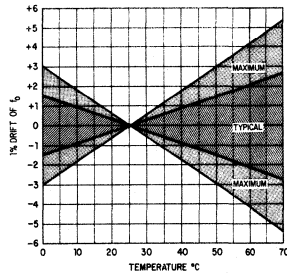
Fig. 3

TYPICAL CHARACTERISTIC CURVES

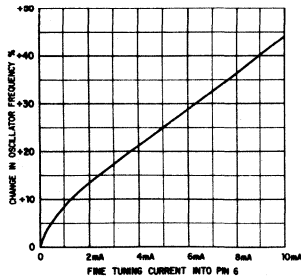
MINIMUM INPUT SIGNAL AMPLITUDE NECESSARY TO MAINTAIN LOCK AS A FUNCTION OF TEMPERATURE WITH  $f_{\text{signal}} = f_0 \pm 25^\circ\text{C} = 2.0 \text{ MHz}$



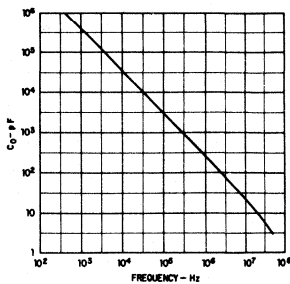
THERMAL DRIFT OF VCO FREE RUNNING FREQUENCY ( $f_0$ )



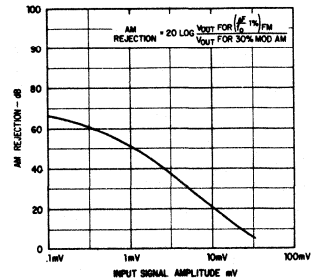
CHANGE OF FREE RUNNING OSCILLATOR FREQUENCY AS A FUNCTION OF FINE TUNING CIRCUIT



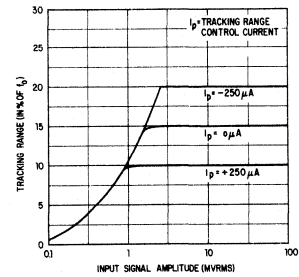
FREE RUNNING OSCILLATOR FREQUENCY AS A FUNCTION OF VCO TIMING CAPACITANCE



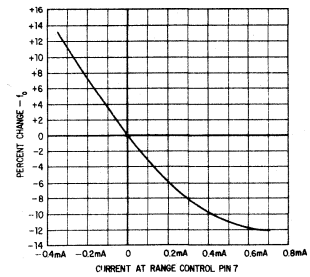
AM REJECTION AS A FUNCTION OF INPUT SIGNAL LEVEL  $f_0 = 10 \text{ MHz}$



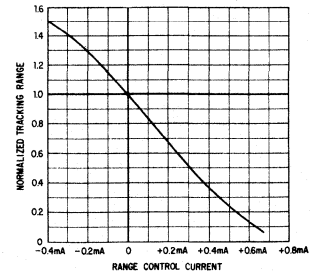
TYPICAL TRACKING RANGE AS A FUNCTION OF INPUT SIGNAL



CHANGE OF FREE RUNNING OSCILLATOR FREQUENCY AS A FUNCTION OF RANGE CONTROL CURRENT



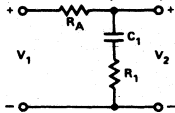
NORMALIZED TRACKING RANGE AS A FUNCTION OF RANGE CONTROL CURRENT



## EXTERNAL CONTROLS

## 1. Loop Low Pass Filter (Pins 14 and 15)

The equivalent circuit for the loop low-pass filter can be represented as:



where  $R_A$  ( $6K \Omega$ ) is the effective resistance seen looking into Pin #14 or Pin #15.

The corresponding filter transfer characteristics are:

$$\frac{V_2}{V_1}(S) = (S) = \frac{1 + S R_1 C_1}{1 + S (R_1 + R_A) C_1}$$

where  $S$  is the complex frequency variable.

## 2. Loop Gain (Threshold) Control

The overall Phase Locked Loop gain can be reduced by connecting a feedback resistor,  $R_F$ , across the low-pass filter terminals, Pins #14 and #15. This causes the loop gain and the detection sensitivity to decrease by a factor  $Q$  ( $Q < 1$ ) where:

$$Q = \frac{R_F}{2 R_A + R_F}$$

Reduction of loop gain may be desirable at high input signal levels ( $V_{in} > 30$  mV) and at high frequencies ( $f_D > 5$  MHz) where excessively high loop gain may cause instability.

## 3. Tracking Range Control (Pin 7)

Any bias current,  $I_P$ , injected into the tracking range control, reduces the tracking range of the PLL by decreasing the output of the limiter. The variation of the tracking range and the center frequency, as a function of  $I_P$ , are shown in the characteristic curves with  $I_P$  defined positive going into the tracking range control terminal. This terminal is normally at a DC level of +0.6 Volts and presents an impedance of  $600 \Omega$ .

## 4. External Fine Tuning (Pin 6)

Any bias current injected into the fine tuning terminal increases the frequency of oscillation,  $f_D$ , as shown in the characteristic curves. This current is defined Positive into the fine tuning terminal. This terminal is at a typical DC level of +1.3 Volts and has a dynamic impedance of  $100 \Omega$  to ground.

## 5. Offset Adjustment (Pin 11)

Application of a bias voltage to the offset adjustment terminal modifies the current in the output amplifier setting the DC level at the output. The effect on the loop is to modify the relationship between the VCO free running frequency and the lock range, allowing the VCO free running frequency to be positioned at different points throughout the lock range.

Nominally this terminal is at +4V DC and has an input impedance of  $3K \Omega$ . The offset adjustment is optional. The characteristics specified correspond to operation of the circuit with this terminal open circuited.

## 6. De-emphasis Filter (Pin 10)

The de-emphasis terminal is normally used when the PLL is used to demodulate Frequency Modulated Audio signals. In this application, a capacitor from this terminal to ground provides the required de-emphasis. For other applications, this terminal may be used for band shaping the output signal. The 3 dB bandwidth of the output amplifier in the system block diagram (see Figure 2.) is related to the de-emphasis capacitor,  $C_D$ , as:

$$f_{3dB} = \frac{1}{2 R_D C_D}$$

where  $R_D$  is the  $8000 \text{ ohm}$  resistance seen looking into the de-emphasis terminal.

When the PLL system is utilized for signal conditioning, and the loop error voltage is not utilized, de-emphasis terminal should be AC grounded.

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE561B Phase Locked Loop (PLL) is a monolithic signal conditioner, and demodulator system comprising a VCO, Phase Comparator, Amplifier and Low Pass Filter, interconnected as shown in the accompanying block diagram. The center frequency of the PLL is determined by the free running frequency ( $f_0$ ) of the VCO. This VCO frequency is set by an external capacitor and can be fine tuned by an optional Potentiometer. The low pass filter, which determines the capture characteristics of the loop is formed by the two capacitors and two resistors at the Phase Comparator output.

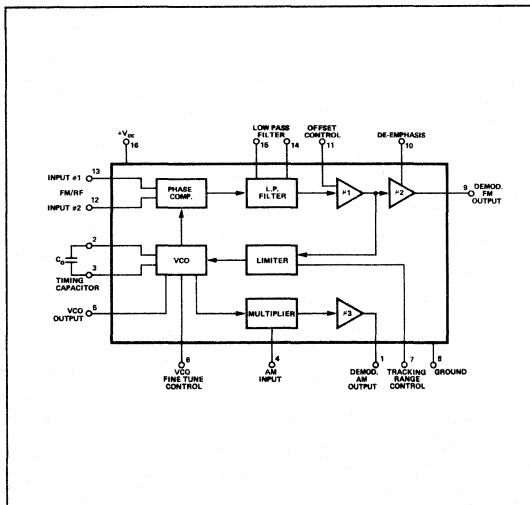
The PLL system has a set of self biased inputs which can be utilized in either a differential or single ended mode. The VCO output is available for signal conditioning, frequency synchronization, multiplication and division applications. Terminals are provided for optional external control of the tracking range, VCO frequency, and output DC level. An analog multiplier block is incorporated into the PLL system to provide frequency selective synchronous AM detection capability.

The monolithic signal conditioner-demodulator system is useful over a wide range of frequencies from less than 1 Hz to more than 15 MHz with an adjustable tracking range of  $\pm 1\%$  to  $\pm 15\%$ .

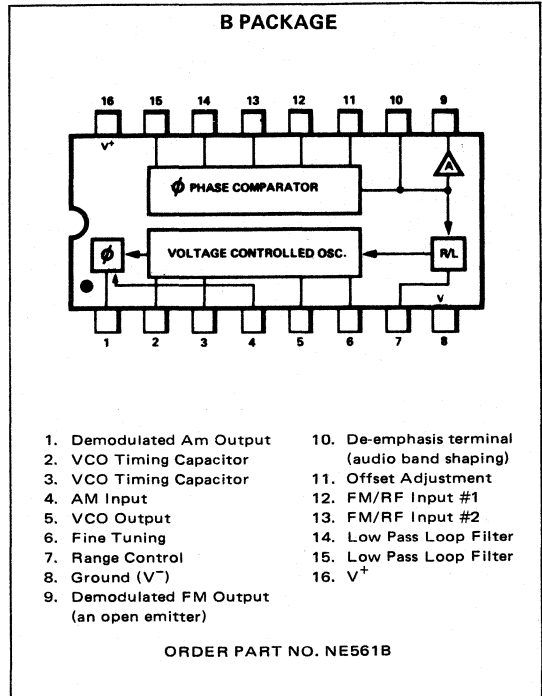
### FEATURES

- FM DEMODULATION WITHOUT TUNED CIRCUITS
- SYNCHRONOUS AM DETECTION
- NARROW BAND PASS TO  $\pm 1\%$
- EXACT FREQUENCY DUPLICATION IN HIGH NOISE ENVIRONMENT
- ADJUSTABLE TRACKING RANGE
- WIDE TRACKING RANGE  $\pm 15\%$
- HIGH LINEARITY - 1% DISTORTION MAX
- FREQUENCY MULTIPLICATION AND DIVISION THROUGH HARMONIC LOCKING

### BLOCK DIAGRAM



### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS

Maximum Operating Voltage	26V
Input Voltage	1V RMS
Storage Temperature	-65°C to 150°C
Operating Temperature	0°C to 70°C
Power Dissipation	300mW

Limiting values above which serviceability may be impaired

### APPLICATIONS

- TONE DECODERS
- AM-FM-IF STRIPS
- TELEMETRY DECODERS
- DATA SYNCHRONIZERS
- SIGNAL RECONSTITUTION
- SIGNAL GENERATORS
- MODEMS
- TRACKING FILTERS
- SCA RECEIVERS
- FSK RECEIVERS
- WIDE BAND HIGH LINEARITY DETECTORS
- SYNCHRONOUS DETECTORS
- AM RECEIVER

**GENERAL ELECTRICAL CHARACTERISTICS**

(15K $\Omega$  Pin 9 to GND, Input Pin 12 or Pin 13 AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
Lowest Practical Operating Frequency		0.1		Hz	Measured at 2 MHz, with both inputs AC grounded Measured at 2 MHz
Maximum Operating Frequency	15	30		MHz	
Supply Current	8	10	12	Ma	
Minimum Input Signal for Lock		100		$\mu$ V	
Dynamic Range		60		dB	
VCO Temp Coefficient*		$\pm 0.06$	$\pm 0.12$	%/°C	
VCO Supply Voltage Regulation		$\pm 0.3$	$\pm 2$	%/V	
Input Resistance		2		k $\Omega$	
Input Capacitance		4		pF	
Input DC Level		+4		V	
Output DC Level	+12	+14	+16	V	Measured at Pin 9 See Figure 3
Available Output Swing		4		V <sub>p-p</sub>	
AM Rejection*	30	40		dB	
De-emphasis Resistance		8		k $\Omega$	

\*ACC Test Sub Group C.

**ELECTRICAL CHARACTERISTICS (For FM Applications, Figure 2) (15K $\Omega$  Pin 9 to GND, Input Pin 12 or 13, AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)**

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
<b>10.7 MHz Operation</b> Deviation 75 kHz    Source Impedance = 50 $\Omega$					
Detection Threshold		120	300	$\mu$ V	Vin = 1 mv Rms    Modulation Frequency 1 kHz Vin = 1 mv Rms    Modulation Frequency 1 kHz Vin = 1 mv Rms    Modulation Frequency 1 kHz
Demodulated Output Amplitude	30	60		mV	
Distortion*		.3	1	% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		35		dB	
<b>4.5 MHz Operation</b> Deviation = 25 kHz, Source Impedance = 50 $\Omega$					
Detection Threshold		120	300	$\mu$ V	Vin = 1 mv Rms    Modulation Frequency 1 kHz Vin = 1 mv Rms    Modulation Frequency 1 kHz Vin = 1 mv Rms    Modulation Frequency 1 kHz
Demodulated Output Amplitude	30	60		mV	
Distortion		0.3	1.0	% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		35		dB	
<b>Wide Deviation</b> $\Delta F/f_0 = 5\%$ Input = 4.5 MHz Deviation = 225 kHz @ 1 kHz modulation rate					
Detection Threshold		1	5	mV	Vin = 5 mv Rms Vin = 5 mv Rms Vin = 5 mv Rms
Demodulated Output	0.2	0.5		Vrms	
Distortion		0.8		% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		50		dB	

\*ACC Test Sub Group C.

**ELECTRICAL CHARACTERISTICS (For Tracking Filter, Figure 1) (15K $\Omega$  Pin 9 to GND, Input Pin 12 or Pin 13 AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)**

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
Tracking Range	$\pm 5$	$\pm 20$		% of f <sub>0</sub>	Vin 5 mv Rms Input 2 MHz - See Characteristic Curves
Minimum Signal to Sustain Lock 0°C to 70°C		0.8		mv Rms	
VCO Output Impedance		1		k $\Omega$	Input 2 MHz Measured with high impedance. Probe with less than 10 pF capacitance.
VCO Output Swing	0.4	0.6		V <sub>p-p</sub>	
VCO Output DC Level		+6.5		V	Input 2 MHz with $\pm 100$ kHz Sideband Separation and 3 kHz Low Pass Filter. Input 1 mv Peak for Carrier and each Sideband C <sub>1</sub> = 0.01 $\mu$ F R <sub>1</sub> = 0
Side Band Suppression		35		dB	

**ELECTRICAL CHARACTERISTICS** (For AM Synchronous Detector, Figure 4) (15KΩ Pin 9 to GND, Input Pin 12 or Pin 13 AC Ground Unused Input, Optional Controls Not Connected, V+ = 18V Unless Otherwise Specified T<sub>A</sub> = 25°C)

CHARACTERISTICS	LIMITS				TEST CONDITIONS
	MIN	TYP	MAX	UNITS	
Input Impedance		3		kΩ	See Definition of Terms See Definition of Terms
Output Impedance		8		kΩ	
Output DC Level	+10	+14	+17	V	
AM Conversion Gain	3	12		dB	
Out of Band Rejection		30		dB	
Distortion		1*		% T.H.D.	

**TYPICAL TEST CIRCUITS**

**TEST CIRCUIT FOR TRACKING FILTER**

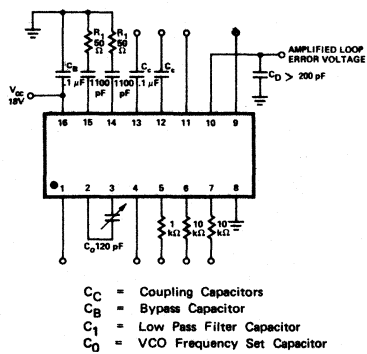


FIGURE 1

**TEST CIRCUIT FOR AM REJECTION**

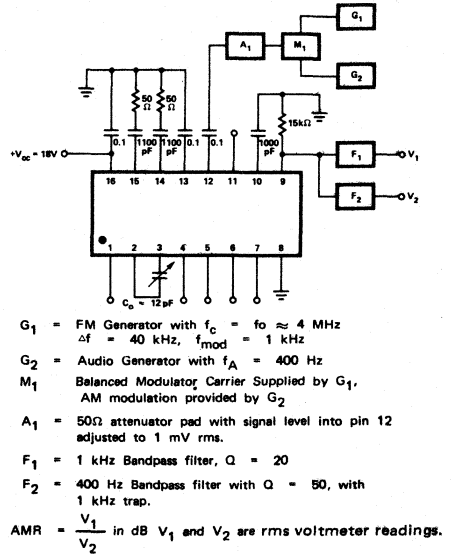


FIGURE 3

**TEST CIRCUIT FOR FM DEMODULATION**

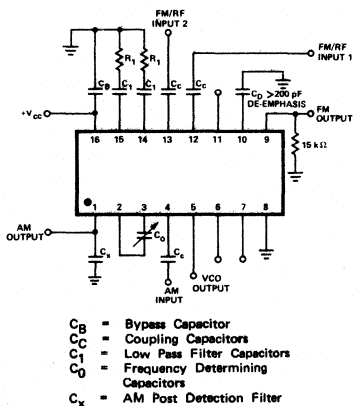


FIGURE 2

**TEST CIRCUIT FOR AM SYNCHRONOUS DETECTOR**

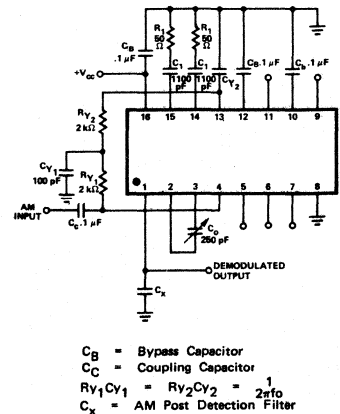
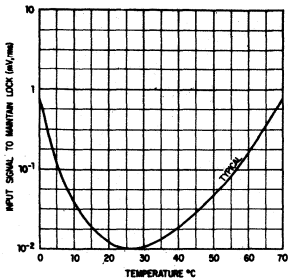


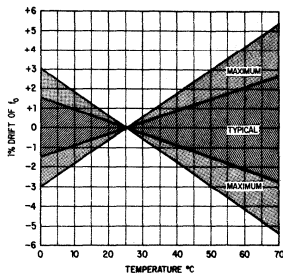
FIGURE 4

TYPICAL CHARACTERISTIC CURVES

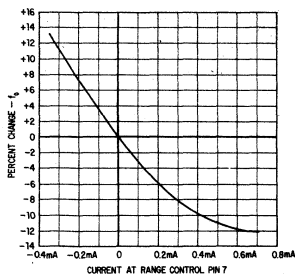
MINIMUM INPUT SIGNAL AMPLITUDE  
NECESSARY TO MAINTAIN LOCK AS A  
FUNCTION OF TEMPERATURE WITH  $f_{\text{signal}}$   
 $= f_{o25^{\circ}\text{C}} = 2.0 \text{ MHz}$



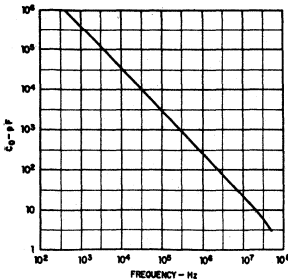
THERMAL DRIFT OF VCO FREE RUNNING  
FREQUENCY ( $f_o$ )



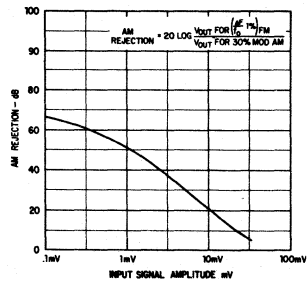
CHANGE OF FREE RUNNING OSCILLATOR  
FREQUENCY AS A FUNCTION OF RANGE  
CONTROL CURRENT



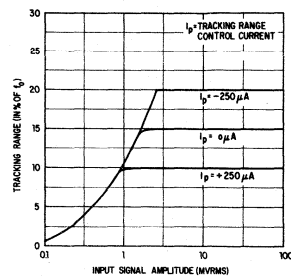
FREE RUNNING OSCILLATOR FREQUENCY  
AS A FUNCTION OF VCO TIMING CAPACITANCE



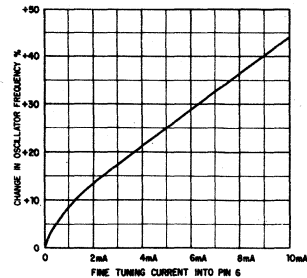
AM REJECTION AS A FUNCTION OF INPUT  
SIGNAL LEVEL  $f_o = 10 \text{ MHz}$



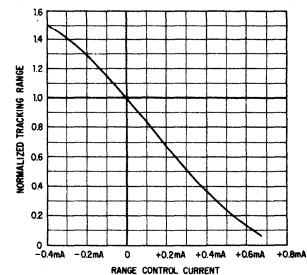
TYPICAL TRACKING RANGE AS A FUNCTION  
OF INPUT SIGNAL



CHANGE OF FREE RUNNING OSCILLATOR  
FREQUENCY AS A FUNCTION OF FINE  
TUNING CIRCUIT



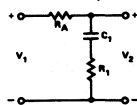
NORMALIZED TRACKING RANGE AS A  
FUNCTION OF RANGE CONTROL CURRENT



**EXTERNAL CONTROLS**

**1. Loop Low Pass Filter (Pins 14 and 15)**

The equivalent circuit for the loop low-pass filter can be represented as:



where RA (6kΩ) is the effective resistance seen looking into Pin # 14 or Pin # 15.

The corresponding filter transfer characteristics are:

$$\frac{V_2}{V_1}(S) = F(S) = \frac{1 + S R_1 C_1}{1 + S (R_1 + R_A) C_1}$$

where S is the complex frequency variable.

**2. Loop Gain (Threshold) Control**

The overall Phase Lock of loop gain can be reduced by connecting a feedback resistor, RF, across the low-pass filter terminals, Pins #14 and #15. This causes the loop gain and the detection sensitivity to decrease by a factor (α < 1), where

$$\alpha = \frac{R_F}{2R_A + R_F}$$

Reduction of loop gain may be desirable at high input signal levels (Vin > 30 mV) and at high frequencies (fo > 5MHz) where excessively high PLL loop gain may cause instability within the loop.

**3. Tracking Range Control (Pin 7)**

Any bias current, Ip, injected into the tracking range control, reduces the tracking range of the PLL by decreasing the output of the limiter. The variation of the tracking range and the center frequency, as a function of Ip, are shown in the characteristic curves with Ip defined positive going into the tracking range control terminal. This terminal is normally at a DC level of +0.6 Volts and presents an impedance of 600Ω.

**4. External Fine Tuning (Pin 6)**

Any bias current injected into the fine tuning terminal increases

the frequency of oscillation, fo, as shown in the characteristic curves. This current is defined Positive into the fine tuning terminal. This terminal is at a typical DC level of +1.3 Volts and has a dynamic impedance of 100Ω to ground.

**5. Offset Adjustment (Pin 11)**

Application of a bias voltage to the offset adjustment terminal modifies the current in the output amplifier setting the DC level at the output. The effect on the loop is to modify the relationship between the VCO free running frequency and the lock range, allowing the VCO free running frequency to be positioned at different points throughout the lock range.

Nominally this terminal is at +4V DC and has an input impedance of 3kΩ. The offset adjustment is optional. The characteristics specified correspond to operation of the circuit with this terminal open circuited.

**6. De-emphasis Filter (Pin 10)**

The de-emphasis terminal is normally used when the PLL is used to demodulate Frequency Modulated Audio signals. In this application, a capacitor from this terminal to ground provides the required de-emphasis. For other applications, this terminal may be used for band shaping the output signal. The 3 dB bandwidth of the output amplifier in the system block diagram (see Figure 2) is related to the de-emphasis capacitor, CD, as:

$$f_{3dB} = \frac{1}{2\pi R_D C_D}$$

where RD is the 8000 ohm resistance seen looking into the de-emphasis terminal.

When the PLL system is utilized for signal conditioning, and the loop error voltage is not utilized, de-emphasis terminal should be AC grounded.

**7. AM Post-Detection Filter (Pin 1)**

The capacitor CX connected between Pin #1 and ground serves as a low-pass filter for synchronous AM detection with a transfer characteristic, F2(S), given as:

$$F_2(S) = \frac{1}{1 + S R_X C_X}$$

where RX = 8kΩ is the resistance seen looking into Pin #1.



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The NE562B Phase Locked Loop (PLL) is a monolithic signal conditioner and demodulator system, comprising a VCO, phase comparator, amplifier and low pass filter, interconnected as shown in the accompanying block diagram. The center frequency of the PLL is determined by the free running frequency ( $f_0$ ) of the VCO. This VCO frequency is set by an external capacitor. The low pass filter, which determines the capture characteristics of the loop, is formed by two capacitors and two resistors at the phase comparator output.

This PLL has two sets of differential inputs, one for the FM/RF input and one for the phase comparator local oscillator input. Both sets of inputs can be used in either a differential or single-ended mode. The FM/RF inputs to the comparator are self-biased. An internally regulated voltage source is provided to bias the phase comparator local oscillator inputs. The VCO output, at high level and in differential form, is available for driving logic circuits in signal conditioning and synchronization, frequency multiplication and division applications. Terminals are also provided for the optional extension of the tracking range. The monolithic signal conditioner-demodulator system is useful over a wide range of frequencies from less than 1 Hz to more than 15 MHz with an adjustable tracking range of  $\pm 1\%$  to  $\pm 15\%$ .

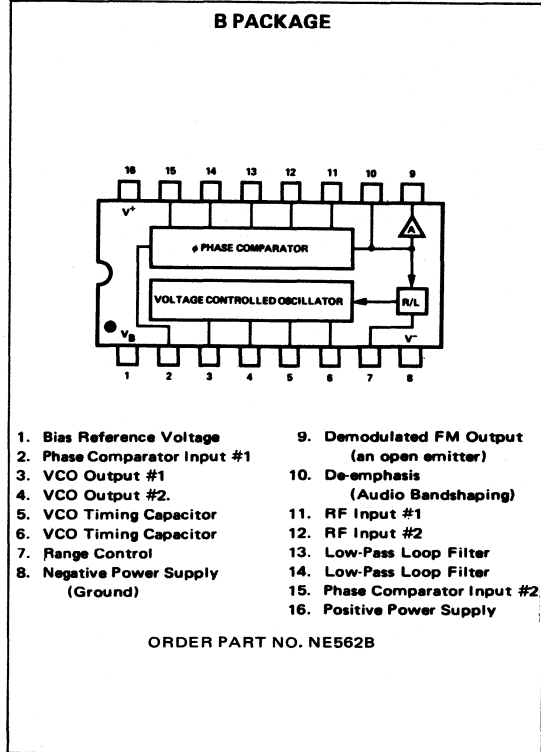
### FEATURES

- FREQUENCY MULTIPLICATION AND DIVISION
- SIGNAL CONDITIONING AND SIDE-BAND SUPPRESSION
- FM DEMODULATION WITHOUT TUNED CIRCUITS
- NARROW BANDPASS - TO  $\pm 1\%$
- ADJUSTABLE TRACKING RANGE - TO  $\pm 15\%$
- EXACT FREQUENCY DUPLICATION IN HIGH NOISE ENVIRONMENT
- HIGH LINEARITY - 1% DISTORTION MAXIMUM AT 1% DEVIATION

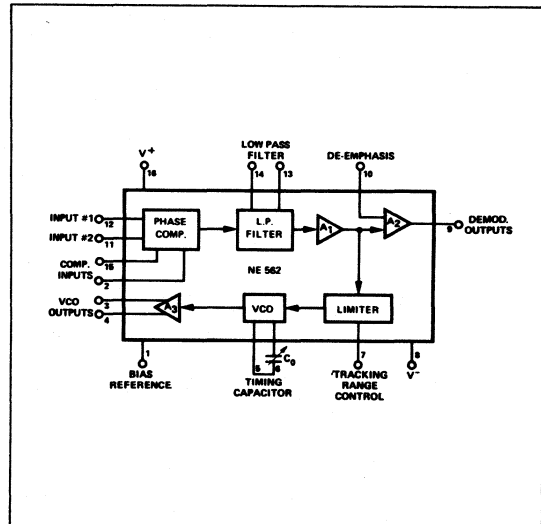
### APPLICATIONS

- FREQUENCY SYNTHESIZERS
- DATA SYNCHRONIZERS
- SIGNAL CONDITIONING
- TRACKING FILTERS
- TELEMETRY DECODERS
- MODEMS
- FM IF STRIPS AND DEMODULATORS
- TONE DECODERS
- FSK RECEIVERS
- WIDEBAND HIGH LINEARITY FM DEMODULATORS

### PIN CONFIGURATION (Top View)



### BLOCK DIAGRAM



# SIGNETICS PHASE LOCKED LOOP ■ 562

## ABSOLUTE MAXIMUM RATINGS (Limiting values above which serviceability may be impaired)

Maximum Operating Voltage	30V
Input Voltage	3V rms
Storage Temperature	-65°C to 150°C
Operating Temperature	0°C to 70°C
Power Dissipation	300mW

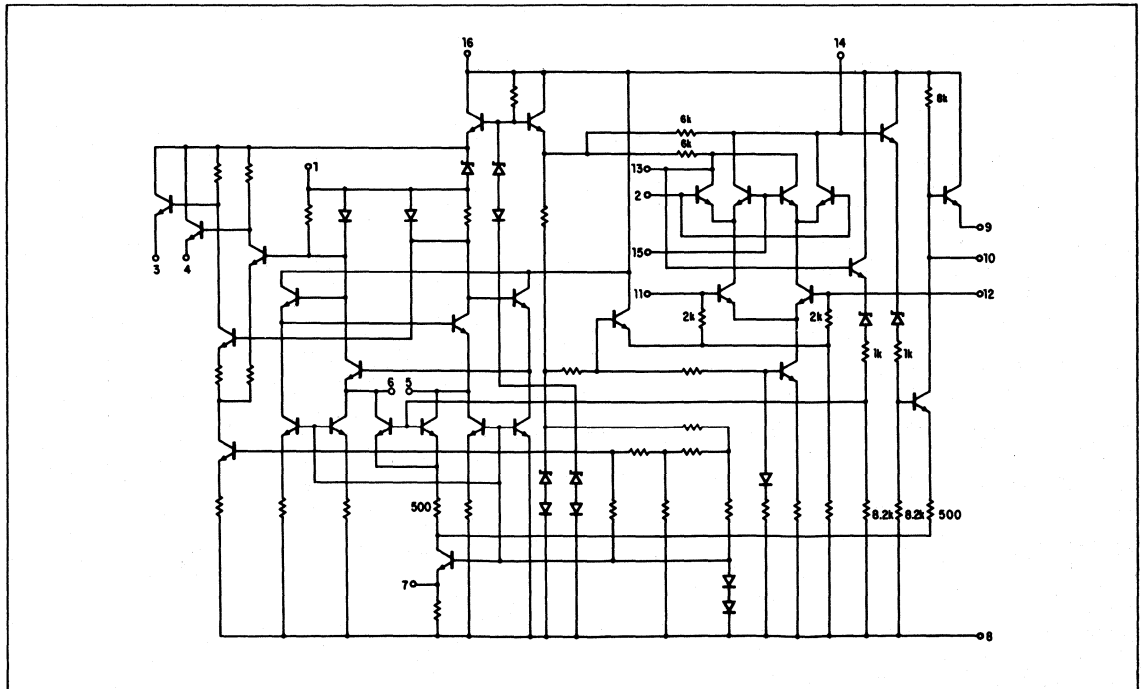
## GENERAL ELECTRICAL CHARACTERISTICS

(15,000 ohms pin 9 to ground, 12,000 ohms pins 3 and 4 to ground, pins 2 and 15 to pin 1 through 1000 ohms, input to pin 11 or 12 with unused input at AC ground, range control not connected and  $V^+ = 18$  volts unless otherwise specified.  $T_A = 25^\circ\text{C}$ .)

CHARACTERISTICS	LIMITS			UNITS	TEST CONDITIONS
	MIN	TYP	MAX		
Lowest Practical Operating Frequency		0.1		Hz	
Maximum Operating Frequency	15	30		MHz	
Supply Current	10	12	14	mA	
Minimum Input Signal for Lock		200		$\mu\text{V}$	
Dynamic Range		80		dB	
VCO Temp Coefficient*		$\pm 0.06$	$\pm 0.15$	$\%/^\circ\text{C}$	Measured at 2 MHz
VCO Supply Voltage Regulation		$\pm 0.3$	$\pm 2$	$\%/V$	Measured at 2 MHz
Input Resistance		2		$k\Omega$	
Input Capacitance		4		pF	
Input DC Level	+12	+14	+16	V	
Output DC Level	+12	+14	+16	V	
Available Output Swing		4		V <sub>p-p</sub>	Measured at Pin 9
AM Rejection*	30	40		dB	See Definition of Terms
De-emphasis Resistance		8		$k\Omega$	
Bias Reference		+8		V	

\* ACC Test Sub Group C.

## SCHEMATIC DIAGRAM



**ELECTRICAL CHARACTERISTICS FOR FM APPLICATIONS** (15,000 ohms pin 9 to ground, input to pin 11 or pin 12, AC ground unused input, range control not connected and  $V^+ = 18$  volts.  $T_A = 25^\circ\text{C}$ .)

CHARACTERISTICS	LIMITS			UNITS	TEST CONDITIONS
	MIN	TYP	MAX		
<b>10.7 MHz Operation</b> Deviation 75 kHz Source Impedance = 50Ω					
Detection Threshold		200	500	μV	$V_{in} = 1$ mV rms Modulation Frequency 1 kHz $V_{in} = 1$ mV rms Modulation Frequency 1 kHz $V_{in} = 1$ mV rms Modulation Frequency 1 kHz
Demodulated Output Amplitude	30	70		mV rms	
Distortion*		0.5		% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		35		dB	
<b>4.5 MHz Operation</b> Deviation = 25 kHz, Source Impedance = 50Ω					
Detection Threshold		200	500	μV	$V_{in} = 1$ mV rms Modulation Frequency 1 kHz $V_{in} = 1$ mV rms Modulation Frequency 1 kHz $V_{in} = 1$ mV rms Modulation Frequency 1 kHz
Demodulated Output Amplitude	30	60		mV rms	
Distortion		0.5		% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		35		dB	
<b>Wide Deviation</b> $\Delta F/f_0 = 5\%$ Input = 4.5 MHz Deviation = 225 kHz @ 1 kHz Modulation Rate					
Detection Threshold		1	5	mV	$V_{in} = 5$ mV rms $V_{in} = 5$ mV rms $V_{in} = 5$ mV rms
Demodulated Output		1		V rms	
Distortion	0.3	0.8		% T.H.D.	
Signal to Noise Ratio $\frac{S+N}{N}$		50		dB	

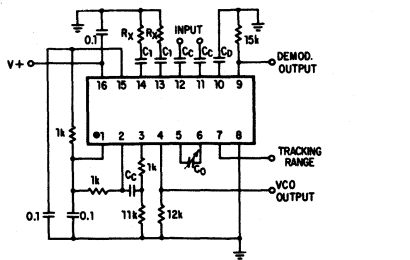
\*ACC Test Sub Group C.

**ELECTRICAL CHARACTERISTICS FOR SIGNAL CONDITIONER AND FREQUENCY SYNTHESIS APPLICATIONS**(Input to pin 11 or pin 12, AC ground unused input, range control not connected,  $V^+ = 18$  volts.  $T_A = 25^\circ\text{C}$ .)

CHARACTERISTIC	LIMITS			UNITS	TEST CONDITIONS
	MIN	TYP	MAX		
Tracking Range	±5	±15		% of $f_0$	200 mV p-p square wave input
Input Resistance		2		kΩ	
Input Capacitance		4		pF	
Input DC Level		4		V	
VCO Output Impedance		1.3	2.5	kΩ	
VCO Output Swing	3	4.5		V p-p	
VCO Output DC Level		12		V	
VCO Signal/Noise Ratio		60		dB	Inputs at AC ground

**TEST CIRCUIT**

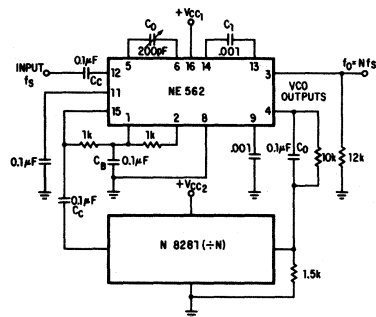
**TEST CIRCUIT FOR FM DEMODULATION**



$C_B$  = Bypass Capacitor  
 $C_C$  = Coupling Capacitor  
 $C_D = .01\mu\text{F}$  for Standard FM  
 Broadcasting  
 $C_1$  and  $R_x$  = Low Pass Filter  
 $C_0$  = Frequency set Capacitor

**FIGURE 1**

**TEST CIRCUIT FOR SIGNAL CONDITIONER AND FREQUENCY SYNTHESIS APPLICATIONS**



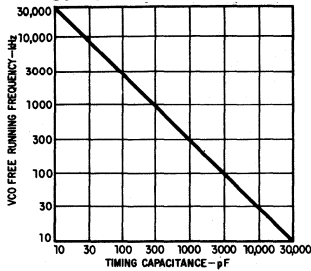
$C_B$  = Bypass Capacitor  
 $C_C$  = Coupling Capacitor  
 $C_1$  = Low Pass Filter Capacitor  
 $C_0$  = Frequency Capacitor Set

Note: Fanout to divide by N counter is one.

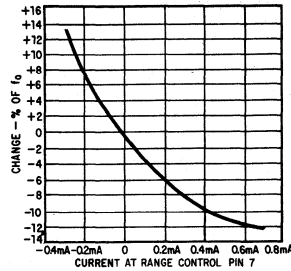
**FIGURE 2**

TYPICAL CHARACTERISTIC CURVES

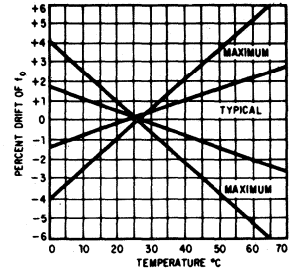
**FREE RUNNING VOLTAGE CONTROLLED OSCILLATOR FREQUENCY AS A FUNCTION OF TIMING CAPACITANCE**



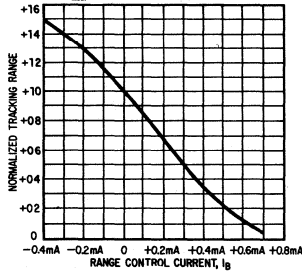
**CHANGE OF FREE RUNNING OSCILLATOR FREQUENCY AS A FUNCTION OF RANGE CONTROL CURRENT**



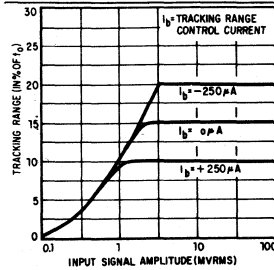
**THERMAL DRIFT OF FREE RUNNING FREQUENCY AS A FUNCTION OF TEMPERATURE**



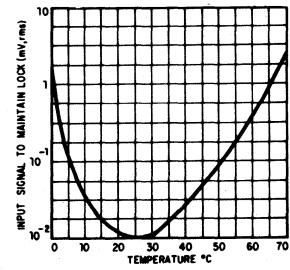
**NORMALIZED TRACKING RANGE AS A FUNCTION OF RANGE CONTROL CURRENT**



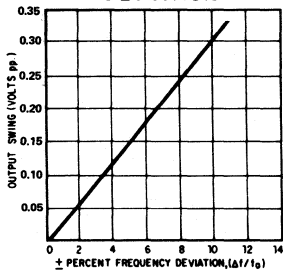
**TYPICAL TRACKING RANGE AS A FUNCTION OF INPUT SIGNAL AMPLITUDE**



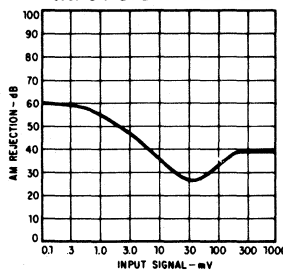
**INPUT SIGNAL AMPLITUDE TO MAINTAIN LOCK AS A FUNCTION OF TEMPERATURE ( $f_{\text{signal}} = f_0 = 2.0 \text{ MHz}$ )**



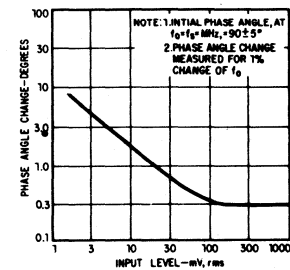
**562 PHASE LOCKED LOOP DEMODULATED OUTPUT SWING AS A FUNCTION OF % FM DEVIATION**



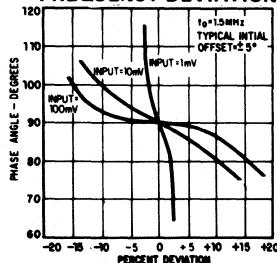
**AM REJECTION AS A FUNCTION OF INPUT SIGNAL LEVEL**



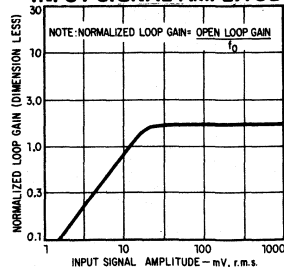
**CHANGE IN PHASE ANGLE,  $f_0$  RELATIVE TO  $f_s$ , AS A FUNCTION OF INPUT SIGNAL AMPLITUDE**



**VCO OUTPUT PHASE AS A FUNCTION OF PERCENT FREQUENCY DEVIATION**



**NORMALIZED LOOP GAIN AS A FUNCTION OF INPUT SIGNAL AMPLITUDE**



**562 APPLICATIONS INFORMATION**

**1. BIAS REFERENCE**

Pin 1 of the 562 is an internally regulated bias reference voltage supply which should be used as a source of bias current for the phase comparator input terminals, Pins 2 and 15. Biasing may be achieved as shown in Figure 3.

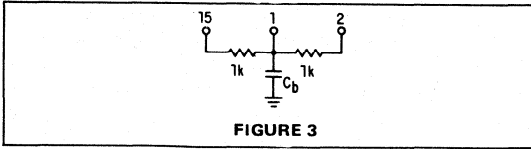


FIGURE 3

**2. PHASE COMPARATOR LOOP INPUTS**

Of the Signetics high frequency phase locked loops, the 562 is unique in that the loop is open between the VCO and the phase comparator. Once biasing of the comparator is accomplished, as described in Bias Reference above, loop closure can be accomplished by capacitive coupling between either one or both inputs of the phase comparator and the VCO output. A divider or counter may be enclosed in the loop at this point for frequency synthesis applications or a flip-flop may be used to ensure that the output waveform has a 50% duty cycle. If large signal swings, greater than 2 volts, are to be applied to the phase comparator inputs, a 1000 ohm current limiting buffer resistor should be used in series with the coupling capacitors.

**3. VCO OUTPUT**

Square wave VCO outputs of both polarities (0°C and 180°C) buffered by an amplifier are available at pins 3 and 4. For proper operation of the buffer amplifier, pins 3 and 4 must be returned to ground (or the negative supply) through resistors, typically 12,000 ohms. The value of these resistors may be reduced provided that total power dissipated in the 562 does not exceed 300 milliwatts or the total average current in each emitter does not exceed 4 mA. The output amplitude is typically 4.5 volts peak referenced at +12 volts with respect to pin 8.

**4. VCO TUNING**

Setting the free-running frequency of the VCO is accomplished easily with one timing capacitor connected between pins 5 and 6. For the 562 Phase Locked Loop, fine tuning of the free-running frequency may be accomplished in either or both of two ways. The first method uses a trimmer capacitor connected in parallel with the VCO timing capacitor. This is the simplest technique and requires the smallest number of extra components but at the lower frequencies may be difficult to implement. The second technique incorporates two resistors and a voltage source. The resistors are connected between each of the timing capacitor terminals and a voltage source as shown in Figure 4.

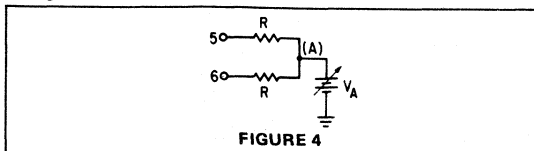
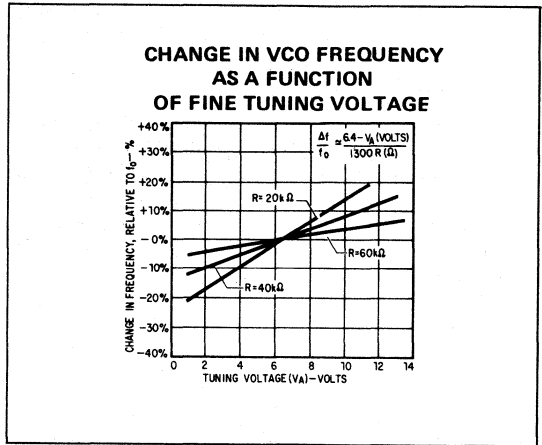


FIGURE 4

The percent change in the VCO free-running frequency,  $f_o$ , as a function of the voltage applied to point (A) is shown in the curves of Figure 5. Note that with this fine tuning technique, it is possible to *increase* the VCO free-running frequency to a value greater than possible with just a trimmer capacitor alone. A formula for the approximation of the VCO frequency as a function of the voltage at point (A), the resistance values and the starting frequency, is given below:

$$f = f_o \left[ 1 - \frac{V_A - 6.4}{1300R} \right]$$

The recommended resistance range of R is 20,000 to 60,000 ohms.



**5. LOOP GAIN CHARACTERISTICS**

The overall open loop gain of the 562 PLL can be expressed as:

$$K_0 = K_1 K_2$$

where:

$K_0$  = total open loop gain

$K_1$  = phase comparator and amplifier conversion gain

$K_2$  = VCO conversion gain

The VCO conversion gain,  $K_2$ , is the change of VCO frequency per unit of error voltage. In this particular design, it is numerically equal to the VCO frequency, i.e.,

$$K_2 = f_o \text{ Hz/Volt}$$

or

$$K_2 = 2\pi f_o \text{ radians/Volt-second}$$

The phase comparator and amplifier conversion gain,  $K_1$ , is proportional to input signal amplitude for low input levels,  $V_s \leq 40\text{mV rms}$ , and it is constant and equal to about 1.5 volts/radian for higher input amplitudes. Therefore,  $K_1$  can be approximated as:

$$K_1 \cong \frac{.04 V_s}{\sqrt{1 + \left(\frac{V_s}{40}\right)^2}}$$

where

$V_s$  = input signal in mV rms.

562 APPLICATIONS INFORMATION (Cont'd.)

6. SIGNAL INPUT

The input structure is basically differential and may be used in this manner. Biasing is supplied to the input terminals from an internal regulated supply so signal inputs must be capacitively coupled. In most applications where the input is single-ended, the unused input should be bypassed to ground.

7. DEMODULATED OUTPUT

Pin 9 is a low impedance output terminal for the loop error voltage. It is at this point that the demodulated FM output is obtained. When used, it must be biased by a resistor to ground (or negative supply), and the resistor value may be adjusted downward provided that the output current does not exceed 5mA or the dissipation in the 562 does not exceed the absolute maximum ratings. When not used, pin 9 may be left open.

8. DE-EMPHASIS FILTER

The de-emphasis terminal, pin 10, is normally required when the PLL is used to demodulate Frequency Modulated Audio signals. In this application, a capacitor from this terminal to ground provides the required de-emphasis. For other applications it may be used to shape the output response. The 3 dB bandwidth of the output amplifier is related to the de-emphasis capacitor,  $C_D$ , as:

$$f_{3dB} = \frac{1}{2\pi R_D C_D}$$

where  $R_D$  is 8000 ohms.

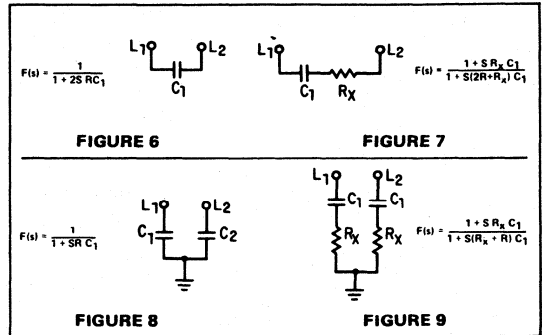
When the PLL system is utilized for applications not requiring the use of the output amplifier, pin 10 should be by-passed to ground.

9. TRACKING RANGE CONTROL (Pin 7)

Any bias current,  $I_p$ , injected into the tracking range control, reduces the tracking range of the PLL by decreasing the output of the limiter. The variation of the tracking range and the center frequency, as a function of  $I_p$ , are shown in the characteristic curves with  $I_p$  defined positive going into the tracking range control terminal. This terminal is normally at a DC level of +0.6 volts and presents an impedance of 600Ω.

10. LOW-PASS FILTER

In most applications, a loop low-pass filter should be connected between pins 13 and 14 and ground. It is used to set the loop response time, controlling the capture range and the rejection of out of band information. Four filter configurations and their transfer functions are shown in Figures 6 through 9. For VCO operating frequencies below 5 MHz, configurations shown in Figures 6 and 7 may be used. At higher frequencies, configurations shown in Figures 8 and 9 should be used to ensure loop stability. R is the impedance seen looking into the low pass filter terminals, Pins 13 and 14; and, in the 562, is nominally 6000 ohms.



11. LOOP GAIN (Threshold) CONTROL

The overall Phase Locked Loop gain can be reduced by connecting a resistor,  $R_F$ , across the low-pass filter terminals, pins 13 and 14. This causes the loop gain and the detection sensitivity to decrease by a factor  $\alpha$ , where:

$$\alpha = \frac{R_F}{12,000 + R_F}$$

Reduction of loop gain may be desirable at operating frequencies greater than 5 MHz because, at these frequencies, high loop gain may cause instability.

12. STATIC LOOP PHASE-ERROR

When the PLL is in lock, the VCO outputs have a nominal  $\pm 90^\circ$  phase shift with respect to the input signal. Due to internal offsets, this nominal angle at perfect lock condition may shift a few degrees, typically  $\pm 5^\circ$  or less.

## LINEAR INTEGRATED CIRCUITS

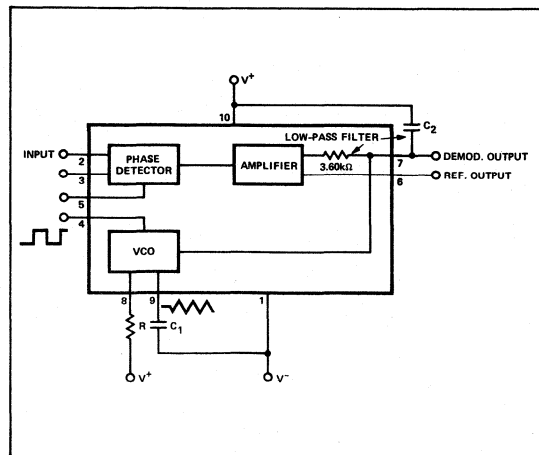
### DESCRIPTION

The SE/NE565 Phase-Locked Loop (PLL) is a self-contained, adaptable filter and demodulator for the frequency range from 0.001 Hz to 500 kHz. The circuit comprises a voltage-controlled oscillator of exceptional stability and linearity, a phase comparator, an amplifier and a low-pass filter as shown in the block diagram. The center frequency of the PLL is determined by the free-running frequency of the VCO; this frequency can be adjusted externally with a resistor or a capacitor. The low-pass filter, which determines the capture characteristics of the loop, is formed by an internal resistor and an external capacitor.

### FEATURES

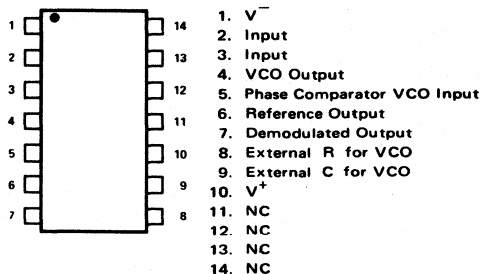
- **EXTREME STABILITY OF CENTER FREQUENCY** (200ppm/°C typ)
- **WIDE RANGE OF OPERATING VOLTAGE** ( $\pm 5$  to  $\pm 12$  VOLTS) WITH VERY SMALL FREQUENCY DRIFT (100ppm/% typ)
- **VERY HIGH LINEARITY OF DEMODULATED OUTPUT** (0.2% typ)
- **CENTER FREQUENCY PROGRAMMING BY MEANS OF A RESISTOR, CAPACITOR, VOLTAGE OR CURRENT**
- **TTL AND DTL COMPATIBLE SQUARE-WAVE OUTPUT; LOOP CAN BE OPENED TO INSERT DIGITAL FREQUENCY DIVIDER**
- **HIGHLY LINEAR TRIANGLE WAVE OUTPUT**
- **REFERENCE OUTPUT FOR CONNECTION OF COMPARATOR IN FREQUENCY DISCRIMINATOR**
- **BANDPASS, ADJUSTABLE FROM  $\leq \pm 1\%$  to  $\geq 60\%$**
- **FREQUENCY ADJUSTABLE OVER 10 TO 1 RANGE WITH SAME CAPACITOR**

### BLOCK DIAGRAM



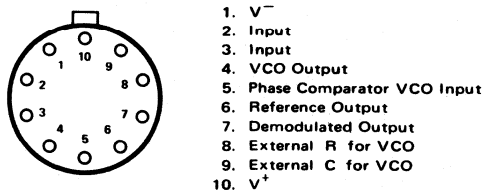
### PIN CONFIGURATIONS (Top View)

#### A PACKAGE



ORDER PART NOS. SE565A/NE565A

#### K PACKAGE



ORDER PART NOS. SE565K/NE565K

### APPLICATIONS

FREQUENCY SHIFT KEYING

MODEMS

TELEMETRY RECEIVERS

TONE DECODERS

SCA RECEIVERS

WIDEBAND FM DISCRIMINATORS

DATA SYNCHRONIZERS

TRACKING FILTERS

SIGNAL RESTORATION

FREQUENCY MULTIPLICATION & DIVISION

# SIGNETICS PHASE LOCKED LOOP ■ 565

## ABSOLUTE MAXIMUM RATINGS (limiting values above which serviceability may be impaired)

Maximum Operating Voltage	26V
Storage Temperature	-65°C to 150°C
Power Dissipation	300mW

## ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ , $V_{CC} = \pm 6$ Volts unless otherwise noted)

PARAMETER	TEST CONDITIONS	SE565			NE565			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
<b>SUPPLY REQUIREMENTS</b>								
Supply Voltage		$\pm 5$		$\pm 12$	$\pm 5$		$\pm 12$	V
Supply Current			8	12.5		8	12.5	mA
<b>INPUT CHARACTERISTICS</b>								
Input Impedance	$-4V \leq V_2, V_3 \leq +1V$	7	10		5	10		$k\Omega$
Input Level Required for Tracking	$f_0 = 50$ kHz $\pm 10\%$ frequency deviation	10	1		10	1		mVrms
<b>VCO CHARACTERISTICS</b>								
Center Frequency								
Maximum Value	$C_1 = 2.7$ pF	300	500			500		kHz
Distribution	Distribution taken about $f_0 \approx 50$ kHz $R_1 = 5.0k, C_1 = 1200$ pF	-10	0	+10	-30	0	+30	%
Drift with Temperature	$f_0 = 50$ kHz	+75	+100	+525		+200		ppm/ $^\circ\text{C}$
Drift with Supply Voltage	$f_0 = 50$ kHz $V_{CC} = \pm 6$ to $\pm 7$ Volts		0.1	1.0		0.2	1.5	%/V
Triangle Wave								
Output Voltage Level			0			0		V
Amplitude		2	2.4	3	2	2.4	3	Vp-p
Linearity			0.2			0.5		%
Square Wave								
Logical "1" Output Voltage	$f_0 = 50$ kHz $V_{CC} = \pm 6$ Volts	+4.9	+5.2		+4.9	+5.2		V
Logical "0" Output Voltage	$f_0 = 50$ kHz $V_{CC} = \pm 6$ Volts		-0.2	+0.2		-0.2	+0.2	V
Duty Cycle	$f_0 = 50$ kHz	45	50	55	40	50	60	%
Rise Time			20	100		20		nsec
Fall Time			50	200		50		nsec
Output Current (sink)		0.6	1		0.6	1		mA
Output Current (source)		5	10		5	10		mA
<b>DEMODULATED OUTPUT CHARACTERISTICS</b>								
Output Voltage Level	(pin 7) $V_{CC} = \pm 6$ Volts	4.25	4.5	4.75	4.0	4.5	5.0	V
Maximum Voltage Swing	(pin 7)		2			2		Vp-p
Output Voltage Swing	$\pm 10\%$ frequency deviation	250	300		200	300		mVp-p
Total Harmonic Distortion			0.2	0.75		0.2	1.5	%
Output Impedance			3.6			3.6		$k\Omega$
Offset Voltage $ V_6 - V_7 $ vs Temperature (drift)	$T_A = 25^\circ\text{C}$		30	100		50	200	mV
AM Rejection		30	40			40		$\mu\text{V}/^\circ\text{C}$ dB

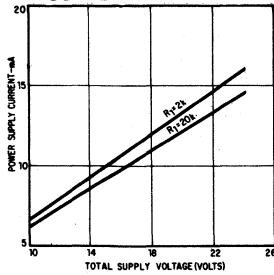
### NOTES:

- Both input terminals (pins 2 and 3) must receive identical dc bias. This bias may range from 0 volts to -4 volts.
- The external resistance for frequency adjustment ( $R_1$ ) must have a value between  $2k\Omega$  and  $20k\Omega$ .
- Output voltage swings negative as input frequency increases.
- Output not buffered.

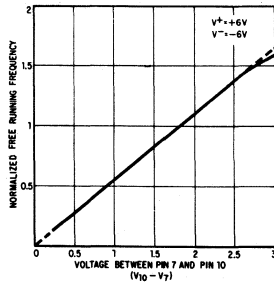


TYPICAL PERFORMANCE CHARACTERISTICS

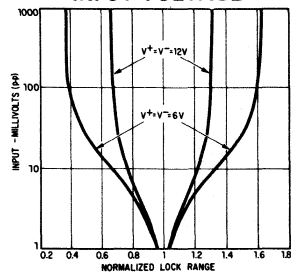
POWER SUPPLY CURRENT AS A FUNCTION OF SUPPLY VOLTAGE



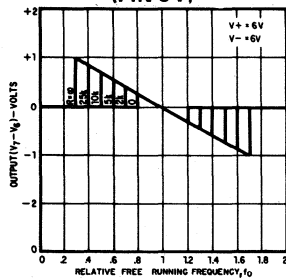
FREE-RUNNING VCO FREQ. AS A FUNCTION OF VOLTAGE BETWEEN PIN 7 & 10 (VCO CONVERSION GAIN)



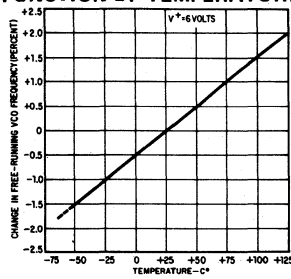
LOCK RANGE AS A FUNCTION OF INPUT VOLTAGE



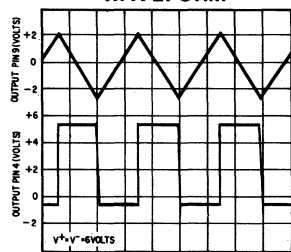
LOCK RANGE AS A FUNCTION OF GAIN SETTING RESISTANCE (PIN 6-7)



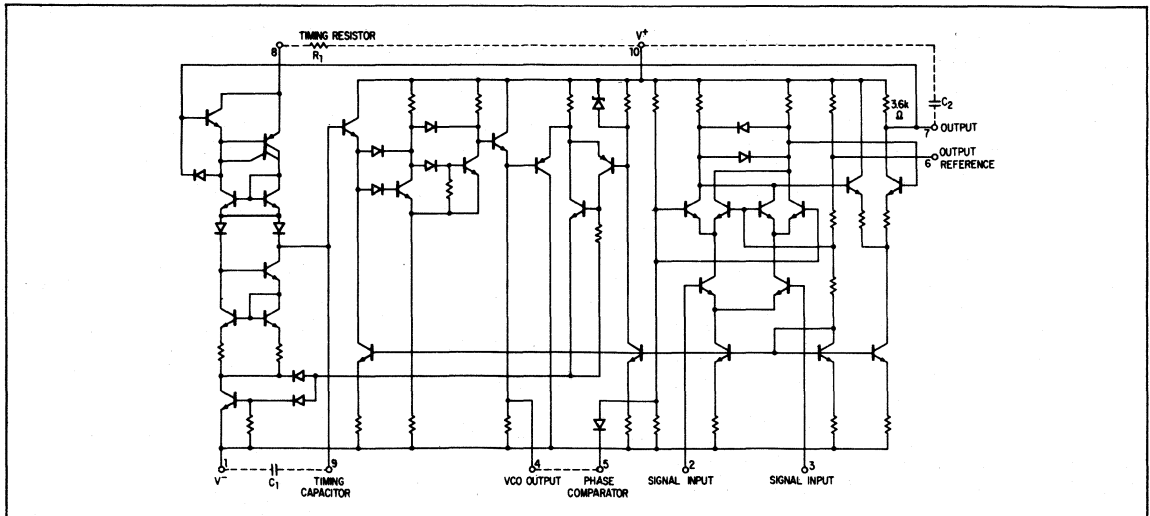
CHANGE IN FREE-RUNNING VCO FREQUENCY AS A FUNCTION OF TEMPERATURE



VCO OUTPUT WAVEFORM



SCHEMATIC DIAGRAM



**DESIGN FORMULAS**

Free-running frequency of VCO  $f_o = \frac{1.2}{4R_1C_1}$  in Hz

Lock-range  $f_L = \pm \frac{8f_o}{V_{cc}}$  in Hz

Capture-range  $f_C \approx \pm \frac{1}{2\pi} \sqrt{\frac{2\pi f_L}{\tau}}$

where  $\tau = (3.6 \times 10^3) \times C_2$

**DEFINITION OF TERMS**

**FREE-RUNNING FREQUENCY ( $f_o$ )**

Frequency of VCO without input signal, both inputs grounded.

**CAPTURE-RANGE**

That range of frequencies about  $f_o$  over which the loop will acquire lock with an input signal initially starting out of lock.

**LOCK-RANGE OR TRACKING-RANGE**

That range of frequencies in the vicinity of  $f_o$  over which the VCO, once locked to the input signal, will remain locked.

**TYPICAL APPLICATIONS**

**FM DEMODULATION**

The 565 Phase Locked Loop is a general purpose circuit designed for highly-linear FM demodulation. During lock, the average dc level of the phase comparator output signal is directly proportional to the frequency of the input signal. As the input frequency shifts, it is this output signal which causes the VCO to shift its frequency to match that of the input. Consequently, the linearity of the phase comparator output with frequency is determined by the voltage-to-frequency transfer function of the VCO.

Because of its unique and highly linear VCO, the 565 PLL can lock to and track an input signal over a very wide range (typically  $\pm 60\%$ ) with very high linearity (typically, within 0.5%).

A typical connection diagram is shown in Figure 1. The VCO free-running frequency is given approximately by

$f_o = \frac{1.2}{4R_1C_1}$  and should be adjusted to be at the center

of the input signal frequency range.  $C_1$  can be any value, but  $R_1$  should be within the range of 2000 to 20,000 ohms with an optimum value on the order of 4000 ohms. The source can be direct coupled if the dc resistances seen from pins 2 and 3 are equal and there is no dc voltage difference between the pins. A short between pins 4 and 5 connects the VCO to the phase comparator. Pin 6 provides a dc reference voltage that is close to the dc potential of the demodulated output (pin 7). Thus, if a resistance ( $R_2$  in Figure 1) is connected between pins 6 and 7, the gain of the output stage can be reduced with little change in the dc voltage level at the output. This allows the lock range to be decreased with little change in the free-running frequency. In this manner the lock range can be decreased from  $\pm 60\%$  of  $f_o$  to approximately  $\pm 20\%$  of  $f_o$  (at  $\pm 6V$ ).

A small capacitor (typically 0.001  $\mu F$ ) should be connected between pins 7 and 8 to eliminate possible oscillation in the control current source.

A single-pole loop filter is formed by the capacitor  $C_2$ , connected between pin 7 and positive supply, and an internal resistance of approximately 3600 ohms.

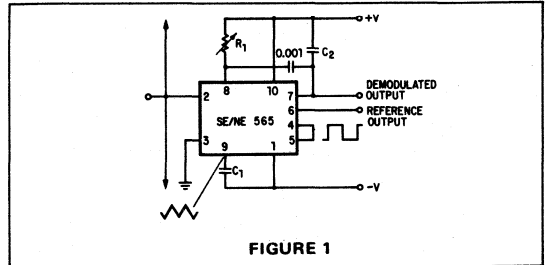


FIGURE 1

**FREQUENCY SHIFT KEYING (FSK)**

FSK refers to data transmission by means of carrier which is shifted between two preset frequencies. This frequency shift is usually accomplished by driving a VCO with the binary data signal so that the two resulting frequencies correspond to the "0" and "1" states (commonly called space and mark) of the binary data signal.

A simple scheme using the 565 to receive FSK signals of 1070 Hz and 1270 Hz is shown in Figure 2. As the signal appears at the input, the loop locks to the input frequency and tracks it between the two frequencies with a corresponding dc shift at the output.

The loop filter capacitor  $C_2$  is chosen smaller than usual to eliminate overshoot on the output pulse, and a three-stage RC ladder filter is used to remove the carrier component from the output. The band edge of the ladder filter is chosen to be approximately half way between the maximum keying rate (in this case 300 baud or 150 Hz) and twice the input frequency (approximately 2200 Hz). The output signal can now be made logic compatible by connecting a voltage comparator between the output and pin 6 of the loop. The free-running frequency is adjusted with  $R_1$  so as to result in a slightly-positive voltage at the output at  $f_{in} = 1070$  Hz.

The input connection is typical for cases where a dc voltage is present at the source and therefore a direct connection is not desirable. Both input terminals are returned to ground with identical resistors (in this case, the values are chosen to effect a 600-ohm input impedance).

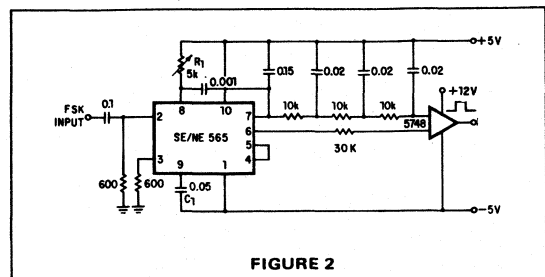


FIGURE 2

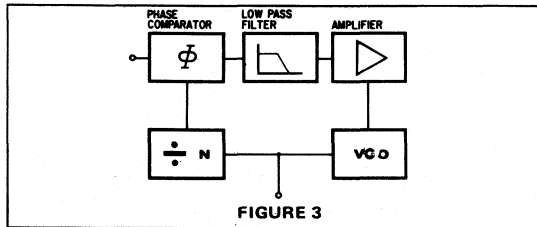
## FREQUENCY MULTIPLICATION

There are two methods by which frequency multiplication can be achieved using the 565:

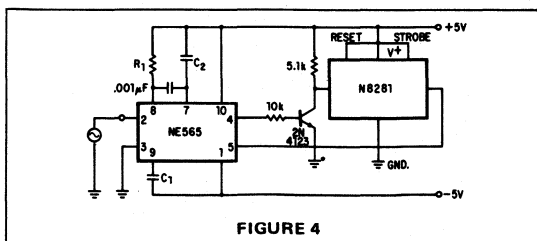
1. Locking to a harmonic of the input signal.
2. Inclusion of a digital frequency divider or counter in the loop between the VCO and phase comparator.

The first method is the simplest, and can be achieved by setting the free-running frequency of the VCO to a multiple of the input frequency. A limitation of this scheme is that the lock range decreases as successively higher and weaker harmonics are used for locking. If the input frequency is to be constant with little tracking required, the loop can generally be locked to any one of the first 5 harmonics. For higher orders of multiplication, or for cases where a large lock range is desired, the second scheme is more desirable. An example of this might be a case where the input signal varies over a wide frequency range and a large multiple of the input frequency is required.

A block diagram of the second scheme is shown in Figure 3. Here the loop is broken between the VCO and the phase comparator, and a frequency divider is inserted. The funda-



mental of the divided VCO frequency is locked to the input frequency in this case, so that the VCO is actually running at a multiple of the input frequency. The amount of multiplication is determined by the frequency divider. A typical connection scheme is shown in Figure 4. To set up the circuit, the frequency limits of the input signal must be determined. The free-running frequency of the VCO is then adjusted by means of  $R_1$  and  $C_1$  (as discussed under FM demodulation) so that the output frequency of the divider is midway between the input frequency limits. The filter capacitor,  $C_2$ , should be large enough to eliminate variations in the demodulated output voltage (at pin 7), in order to stabilize the VCO frequency. The output can now be taken as the VCO squarewave output, and its fundamental will be the desired multiple of the input frequency ( $f_1$ ) as long as the loop is in lock.



## SCA (BACKGROUND MUSIC) DECODER

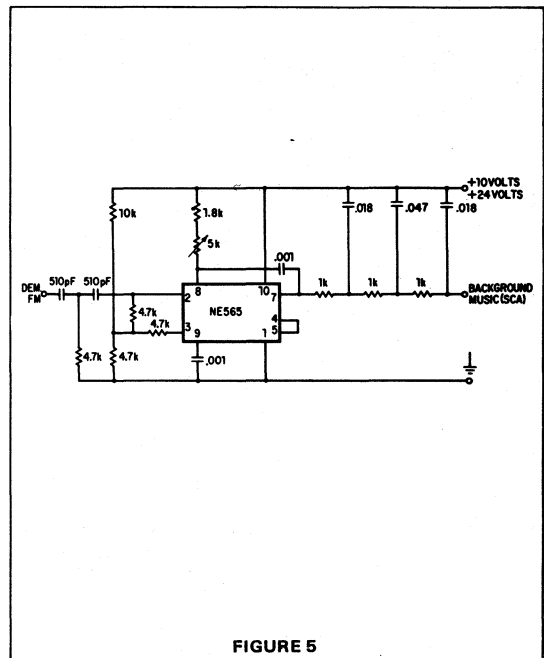
Some FM stations are authorized by the FCC to broadcast uninterrupted background music for commercial use. To do this a frequency modulated subcarrier of 67 kHz is used. The frequency is chosen so as not to interfere with the normal stereo or monaural program; in addition, the level of the subcarrier is only 10% of the amplitude of the combined signal.

The SCA signal can be filtered out and demodulated with the NE565 Phase Locked Loop without the use of any resonant circuits. A connection diagram is shown in Figure 5. This circuit also serves as an example of operation from a single power supply.

A resistive voltage divider is used to establish a bias voltage for the input (pins 2 and 3). The demodulated (multiplex) FM signal is fed to the input through a two-stage high-pass filter, both to effect capacitive coupling and to attenuate the strong signal of the regular channel. A total signal amplitude, between 80 mV and 300 mV, is required at the input. Its source should have an impedance of less than 10,000 ohms.

The Phase Locked Loop is tuned to 67 kHz with a 5000 ohm potentiometer; only approximate tuning is required, since the loop will seek the signal.

The demodulated output (pin 7) passes through a three-stage low-pass filter to provide de-emphasis and attenuate the high-frequency noise which often accompanies SCA transmission. Note that no capacitor is provided directly at pin 7; thus, the circuit is operating as a first-order loop. The demodulated output signal is in the order of 50 mV and the frequency response extends to 7 kHz.



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The SE/NE 566 Function Generator is a voltage controlled oscillator of exceptional stability and linearity with buffered square wave and triangle wave outputs. The frequency of oscillation is determined by an external resistor and capacitor and the voltage applied to the control terminal. The oscillator can be programmed over a ten to one frequency range by proper selection of an external resistance and modulated over a ten to one range by the control voltage, with exceptional linearity.

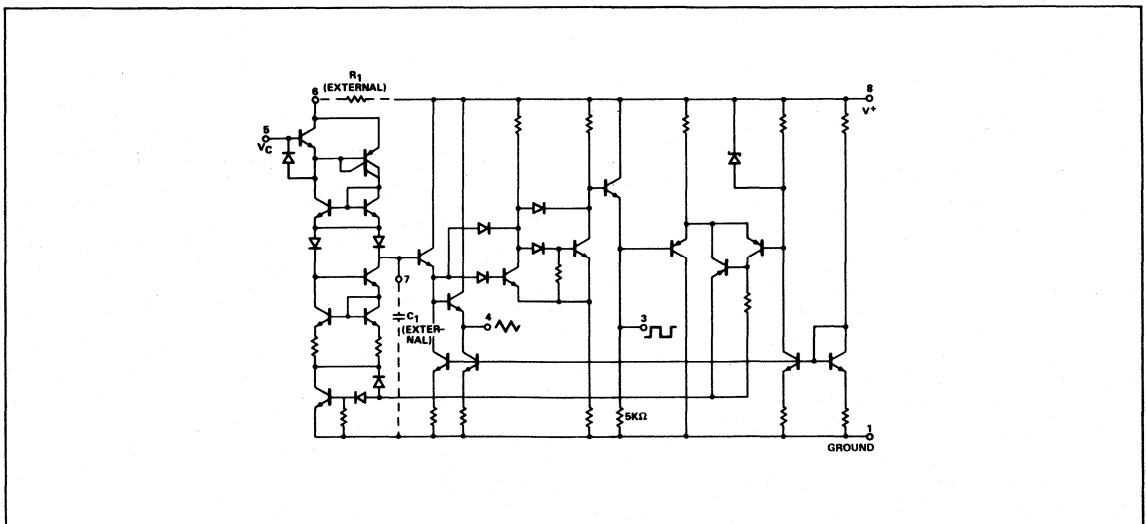
### FEATURES

- WIDE RANGE OF OPERATING VOLTAGE (10 to 24 volts)
- VERY HIGH LINEARITY OF MODULATION
- EXTREME STABILITY OF FREQUENCY (100 ppm/°C typical)
- HIGHLY LINEAR TRIANGLE WAVE OUTPUT
- HIGH ACCURACY SQUARE WAVE OUTPUT
- FREQUENCY PROGRAMMING BY MEANS OF A RESISTOR, CAPACITOR, VOLTAGE OR CURRENT
- FREQUENCY ADJUSTABLE OVER 10 TO 1 RANGE WITH SAME CAPACITOR

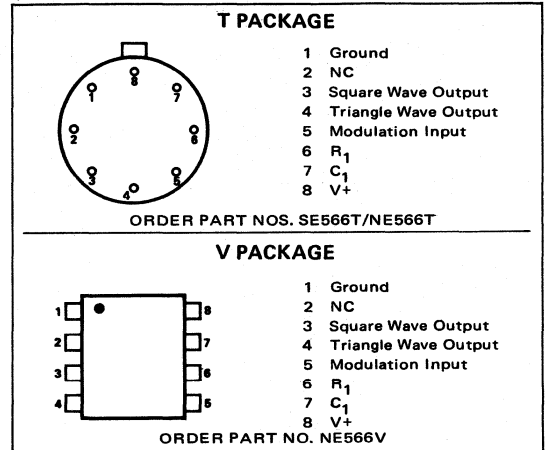
### APPLICATIONS

- TONE GENERATORS
- FREQUENCY SHIFT KEYING
- FM MODULATORS
- CLOCK GENERATORS
- SIGNAL GENERATORS
- FUNCTION GENERATORS

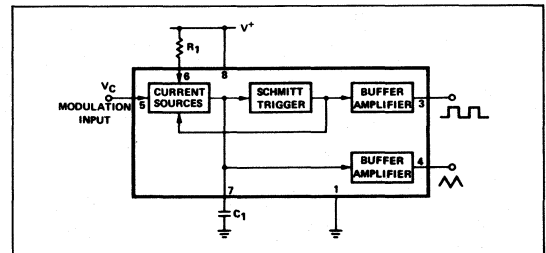
### EQUIVALENT CIRCUIT



### PIN CONFIGURATION (Top View)



### BLOCK DIAGRAM



**ABSOLUTE MAXIMUM RATINGS** (Limiting values above which serviceability may be impaired)

Maximum Operating Voltage 26V  
 Storage Temperature -65°C to 150°C  
 Power Dissipation 300mW

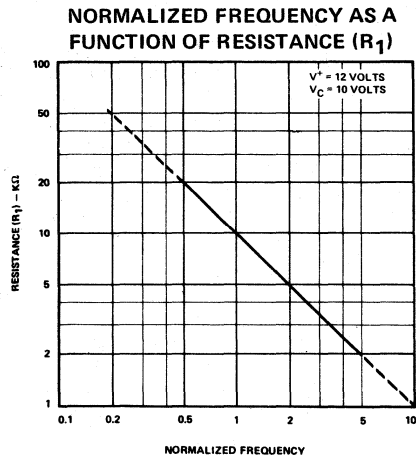
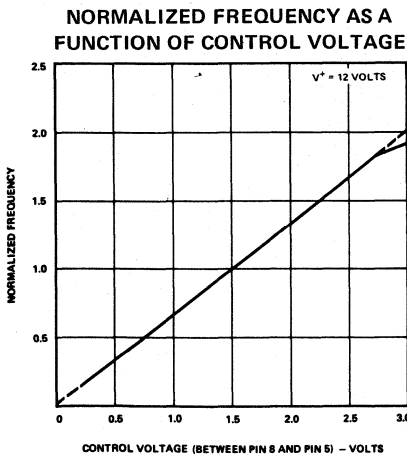
**ELECTRICAL CHARACTERISTICS** (25°C, 12 Volts, unless otherwise stated)

CHARACTERISTICS	SE566			NE566			UNITS
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
<b>GENERAL</b>							
Operating Temperature Range	-55		125	0		70	°C
Operating Supply Voltage			24			24	Volts
Operating Supply Current		7	12.5		7	12.5	mA
<b>VCO (Note 1)</b>							
Maximum Operating Frequency		1			1		MHz
Frequency Drift with Temperature		100			200		ppm/°C
Frequency Drift with Supply Voltage		1			2		%/volt
Control Terminal Input Impedance (Note 2)		1			1		MΩ
FM Distortion (±10% Deviation)		0.2	0.75		0.2	1.5	%
Maximum Sweep Rate		1			1		MHz
Sweep Range		10:1			10:1		
<b>OUTPUT</b>							
<b>Triangle Wave Output -</b>							
Impedance		50			50		Ω
Voltage	2	2.4		2	2.4		Volts pp
Linearity		0.2			0.5		%
<b>Square Wave Output -</b>							
Impedance		50			50		Ω
Voltage	5	5.4		5	5.4		Volts pp
Duty Cycle	45	50	55	40	50	60	%
Rise Time		20			20		nsec
Fall Time		50			50		nsec

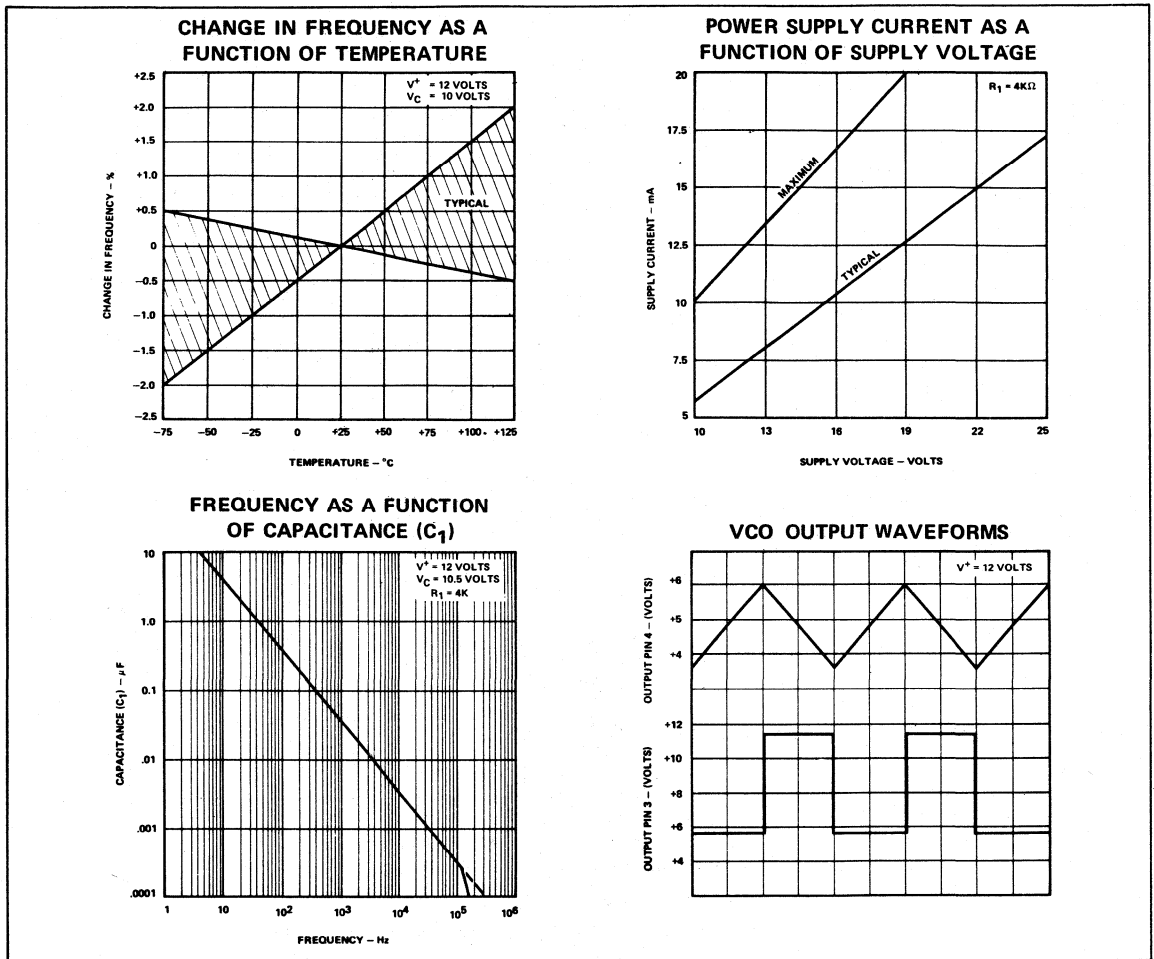
**NOTES:**

1. The external resistance for frequency adjustment ( $R_1$ ) must have a value between  $2K\Omega$  and  $20K\Omega$ .
2. The bias voltage ( $V_c$ ) applied to the control terminal (pin 5) should be in the range  $3/4 V^+ < V_c < V^+$ .

**TYPICAL PERFORMANCE CHARACTERISTICS**



TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)



OPERATING INSTRUCTIONS

The SE/NE 566 Function Generator is a general purpose voltage controlled oscillator designed for highly linear frequency modulation. The circuit provides simultaneous square wave and triangle wave outputs at frequencies up to 1 MHz. A typical connection diagram is shown in Figure 1. The control terminal (pin 5) must be biased externally with a voltage (V<sub>C</sub>) in the range

$$3/4 V^+ \leq V_C \leq V^+$$

where V<sub>CC</sub> is the total supply voltage. In Figure 1, the control voltage is set by the voltage divider formed with R<sub>2</sub> and R<sub>3</sub>. The modulating signal is then ac coupled with the capacitor C<sub>2</sub>. The modulating signal can be direct coupled as well, if the appropriate dc bias voltage is applied to the control terminal. The frequency is given approximately by

$$f_o \approx \frac{2(V^+ - V_C)}{R_1 C_1 V^+}$$

and R<sub>1</sub> should be in the range 2K < R<sub>1</sub> < 20KΩ. A small capacitor (typically 0.001μf) should be connected between pins 5 and 6 to eliminate possible oscillation in the control current source.

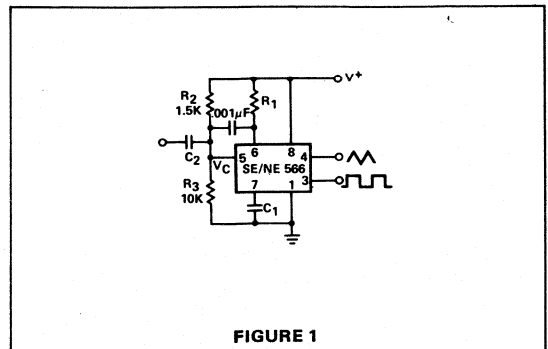
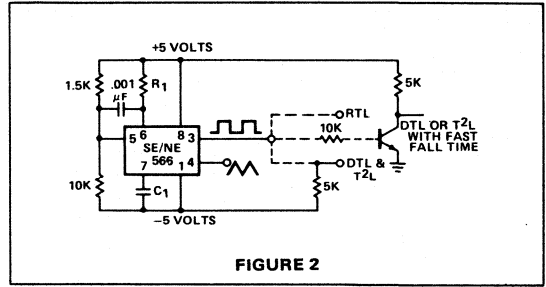


FIGURE 1

**OPERATING INSTRUCTIONS (Cont'd)**

If the VCO is to be used to drive standard logic circuitry, it may be desirable to use a dual supply of  $\pm 5$  volts as shown in Figure 2. In this case the square wave output has the proper dc levels for logic circuitry. RTL can be driven directly from pin 3. For DTL or T<sup>2</sup>L gates, which require a current sink of more than 1 mA, it is usually necessary to connect a 5K $\Omega$  resistor between pin 3 and negative supply. This increases the current sinking capability to 2 mA. The third type of interface shown uses a saturated transistor between the 566 and the logic circuitry. This scheme is used primarily for T<sup>2</sup>L circuitry which requires a fast fall time (< 50 nsec) and a large current sinking capability.



**FIGURE 2**

### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

The SE/NE 567 tone and frequency decoder is a highly stable phase-locked loop with synchronous AM lock detection and power output circuitry. Its primary function is to drive a load whenever a sustained frequency within its detection band is present at the self-biased input. The bandwidth center frequency, and output delay are independently determined by means of four external components.

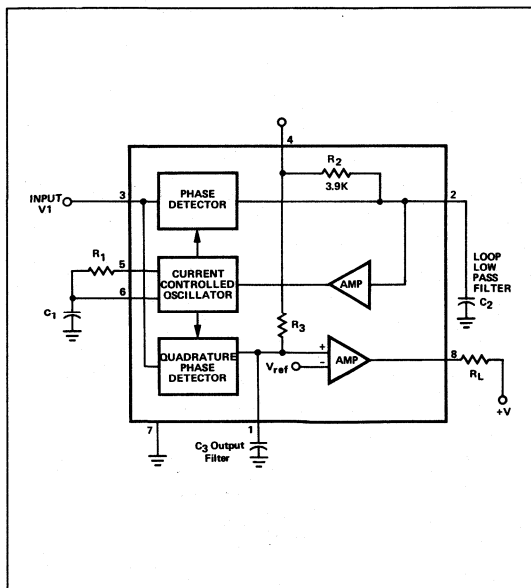
#### FEATURES

- WIDE FREQUENCY RANGE (.01Hz TO 500kHz)
- HIGH STABILITY OF CENTER FREQUENCY
- INDEPENDENTLY CONTROLLABLE BANDWIDTH (0 TO 14 PERCENT)
- HIGH OUT-BAND SIGNAL AND NOISE REJECTION
- LOGIC-COMPATIBLE OUTPUT WITH 100mA CURRENT SINKING CAPABILITY
- INHERENT IMMUNITY TO FALSE SIGNALS
- FREQUENCY ADJUSTMENT OVER A 20 TO 1 RANGE WITH AN EXTERNAL RESISTOR

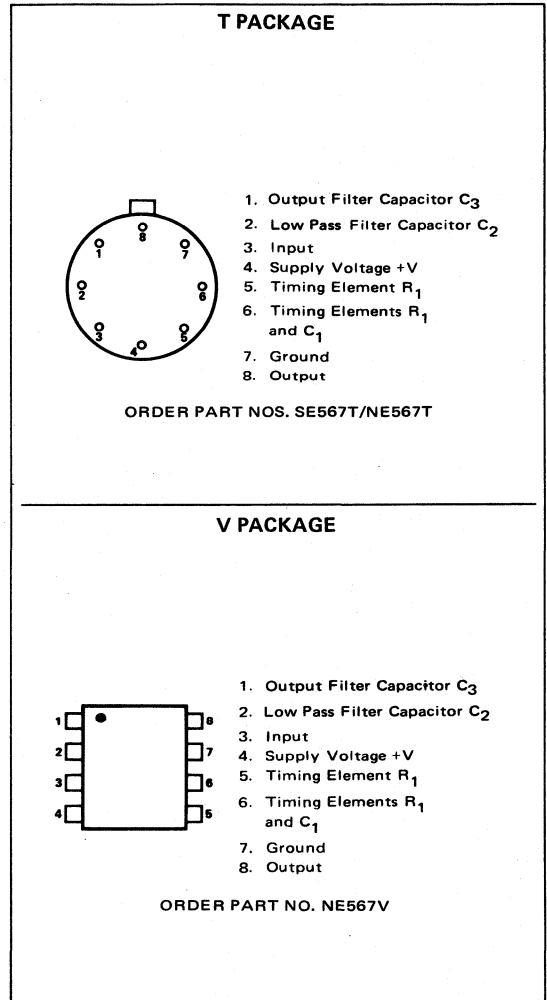
#### APPLICATIONS

- TOUCH TONE<sup>®</sup> DECODING
- CARRIER CURRENT REMOTE CONTROLS
- ULTRASONIC CONTROLS (REMOTE TV, ETC.)
- COMMUNICATIONS PAGING
- FREQUENCY MONITORING AND CONTROL
- WIRELESS INTERCOM
- PRECISION OSCILLATOR

#### BLOCK DIAGRAM



#### PIN CONFIGURATION (Top View)



#### ABSOLUTE MAXIMUM RATINGS

Operating Temperature	0°C to 70°C NE567
	-55°C to 125°C SE567
Operating Voltage	10V
Positive Voltage at Input	0.5V above Supply Voltage (Pin 4)
Negative Voltage at Input	-10 VDC
Output Voltage (collector of output transistor)	15 VDC
Storage Temperature	-65°C to 150°C
Power Dissipation	300mW



ELECTRICAL CHARACTERISTICS (V+ = 5.0 Volts, T<sub>A</sub> = 25°C unless noted)

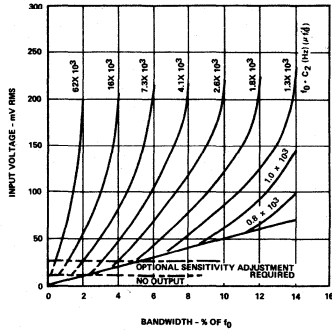
CHARACTERISTICS	SE567			NE567			UNITS	TEST CONDITIONS
	MIN	TYP	MAX	MIN	TYP	MAX		
<b>CENTER FREQUENCY(NOTE 1)</b>								
Highest Center Frequency (f <sub>o</sub> )	100	500		100	500		kHz	
Center Frequency Stability (Note 2)		35±140 35±60			35±140 35±60		ppm/°C ppm/°C	-55 to 125°C 0 to 70°C
Center Frequency Shift with Supply Voltage		0.5	1		0.7	2	%/Volt	f <sub>o</sub> = 100KHz
<b>DETECTION BANDWIDTH</b>								
Largest Detection Bandwidth	12	14	16	10	14	18	% of f <sub>o</sub>	f <sub>o</sub> = 100KHz
Largest Detection Bandwidth Skew		1	2		2	3	% of f <sub>o</sub>	
Largest Detection Bandwidth - Variation with Temperature		±0.1			±0.1		%/°C	V <sub>i</sub> = 300mVrms
Largest Detection Bandwidth - Variation with Supply Voltage		±2			±2		%/Volt	V <sub>i</sub> = 300mVrms
<b>INPUT</b>								
Input Resistance		20			20		KΩ	
Smallest Detectable Input Voltage(V <sub>i</sub> )		20	25		20	25	mV rms	I <sub>L</sub> = 100mA, f <sub>i</sub> = f <sub>o</sub>
Largest No-Output Input Voltage	10	15		10	15		mV rms	I <sub>L</sub> = 100mA, f <sub>i</sub> = f <sub>o</sub>
Greatest Simultaneous Outband Signal to Inband Signal Ratio		+6			+6		dB	
Minimum Input Signal to Wideband Noise Ratio		-6			-6		dB	B <sub>n</sub> = 140KHz
<b>OUTPUT</b>								
Fastest On-Off Cycling Rate		f <sub>o</sub> /20			f <sub>o</sub> /20			
"1" Output Leakage Current		0.01	25		0.01	25	μA	
"0" Output Voltage		0.2 0.6	0.4 1.0		0.2 0.6	0.4 1.0	Volt Volt	I <sub>L</sub> = 30mA I <sub>L</sub> = 100mA
Output Fall Time (Note 3)		30			30		n sec	R <sub>L</sub> = 50Ω
Output Rise Time (Note 3)		150			150		n sec	R <sub>L</sub> = 50Ω
<b>GENERAL</b>								
Operating Voltage Range	4.75		9.0	4.75		9.0	Volts	
Supply Current - Quiescent		6	8		7	10	mA	
Supply Current - Activated		11	13		12	15	mA	R <sub>L</sub> = 20KΩ
Quiescent Power Dissipation		30			35		mW	

## NOTES:

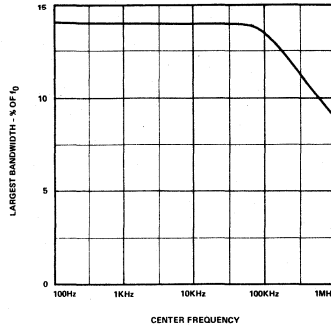
1. Frequency determining resistor R<sub>1</sub> should be between 1 and 20KΩ.
2. Applicable over 4.75 to 5.75 volts. See graphs for more detailed information.
3. Pin 8 to Pin 1 feedback R<sub>L</sub> network selected to eliminate pulsing during turn-on and turn-off.

TYPICAL CHARACTERISTIC CURVES

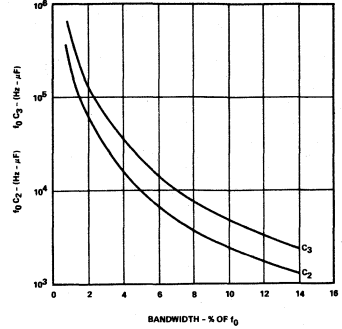
**BANDWIDTH VERSUS INPUT SIGNAL AMPLITUDE**



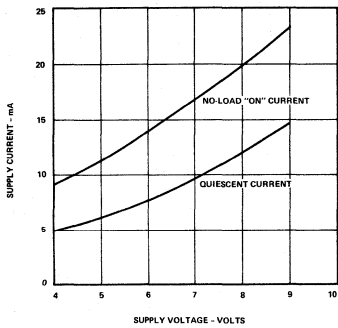
**LARGEST DETECTION BANDWIDTH VERSUS OPERATING FREQUENCY**



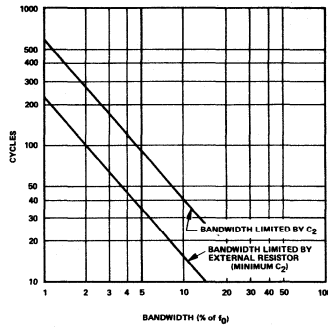
**DETECTION BANDWIDTH AS A FUNCTION OF  $C_2$  AND  $C_3$**



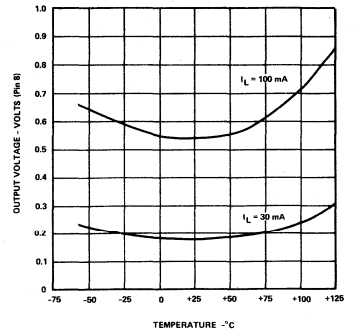
**TYPICAL SUPPLY CURRENT VERSUS SUPPLY VOLTAGE**



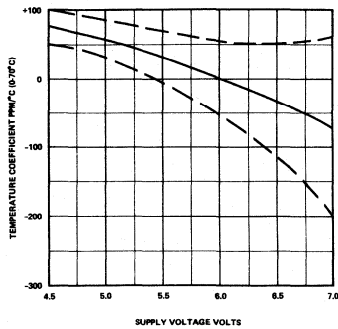
**GREATEST NUMBER OF CYCLES BEFORE OUTPUT**



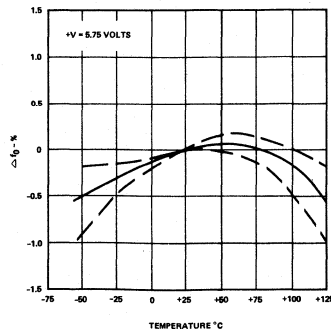
**TYPICAL OUTPUT VOLTAGE VERSUS TEMPERATURE**



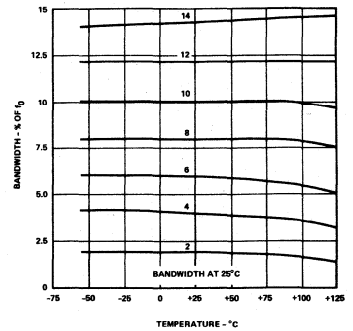
**CENTER FREQUENCY COEFFICIENT TEMPERATURE (MEAN AND S.D.)**



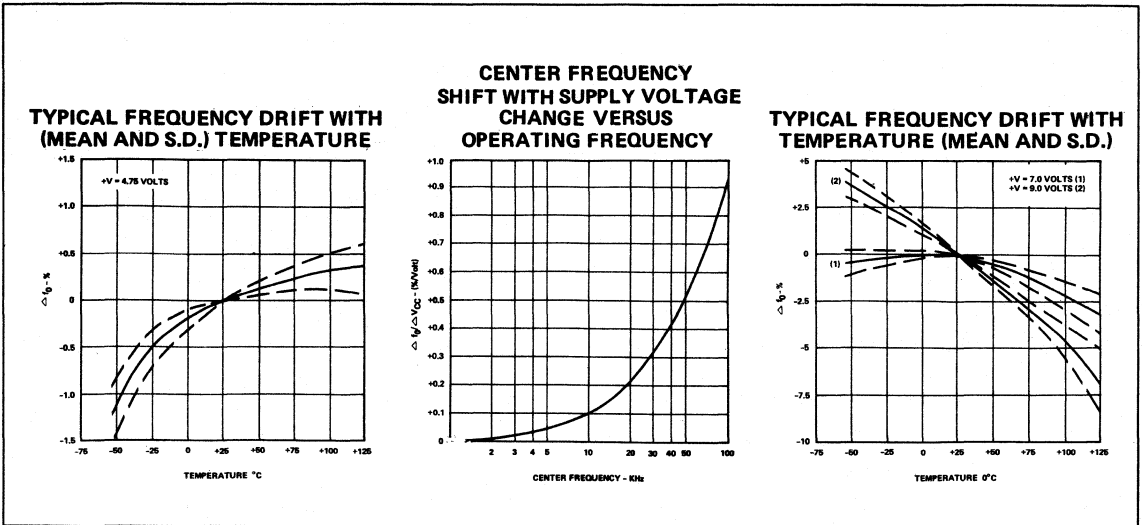
**TYPICAL FREQUENCY DRIFT WITH TEMPERATURE (MEAN AND S.D.)**



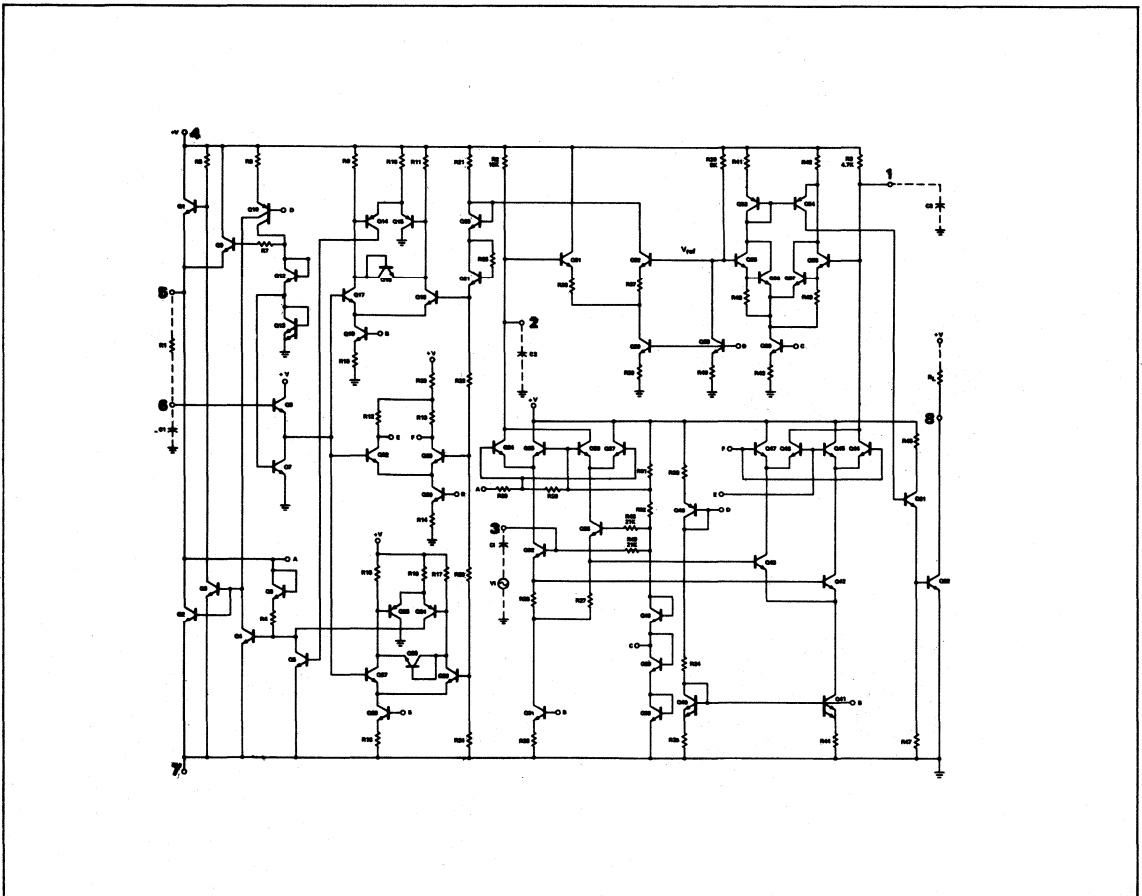
**TYPICAL BANDWIDTH VARIATION WITH TEMPERATURE**



TYPICAL CHARACTERISTIC CURVES (Cont'd.)



SCHEMATIC DIAGRAM



**DESIGN FORMULAS**

$$f_0 \approx \frac{1.1}{R_1 C_1}$$

$$BW \approx 1070 \sqrt{\frac{V_i}{f_0 C_2}} \text{ in \% of } f_0, V_{IN} < 200\text{mV (RMS)}$$

Where

$V_i$  = Input Voltage (Volts RMS)  
 $C_2$  = Low-Pass Filter Capacitor ( $\mu\text{F}$ )

**PHASE LOCKED LOOP TERMINOLOGY  
 CENTER FREQUENCY ( $f_0$ )**

The free-running frequency of the current controlled oscillator (CCO) in the absence of an input signal.

**DETECTION BANDWIDTH (BW)**

The frequency range, centered about  $f_0$ , within which an input signal above the threshold voltage (typically 20mV rms) will cause a logical zero state on the output. The detection bandwidth corresponds to the loop capture range.

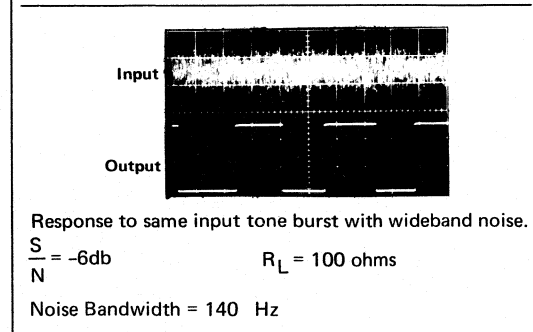
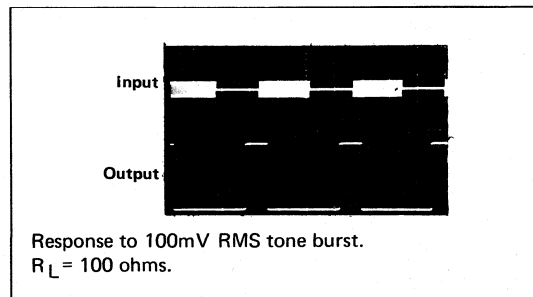
**LARGEST DETECTION BANDWIDTH**

The largest frequency range within which an input signal above the threshold voltage will cause a logical zero state on the output. The maximum detection bandwidth corresponds to the loop lock range.

**DETECTION BAND SKEW**

A measure of how well the largest detection band is centered about the center frequency,  $f_0$ . The skew is defined as  $(f_{\text{max}} + f_{\text{min}} - 2f_0)/f_0$  where  $f_{\text{max}}$  and  $f_{\text{min}}$  are the frequencies corresponding to the edges of the detection band. The skew can be reduced to zero if necessary by means of an optional centering adjustment.

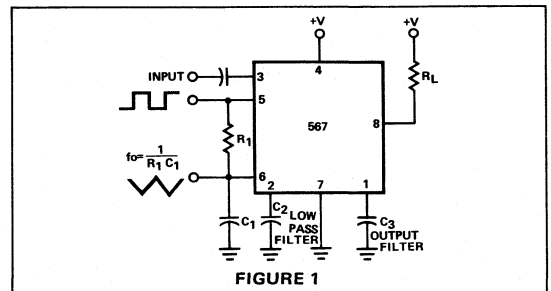
**TYPICAL RESPONSE**



**OPERATING INSTRUCTIONS**

Figure 1 shows a typical connection diagram for the 567. For most applications, the following three-step procedure will be sufficient for choosing the external components  $R_1$ ,  $C_1$ ,  $C_2$  and  $C_3$ .

1. Select  $R_1$  and  $C_1$  for the desired center frequency. For best temperature stability,  $R_1$  should be between 2K and 20K ohm, and the  $R_1 C_1$  product should have sufficient stability, over the projected temperature range to meet the necessary requirements.
2. Select the low-pass capacitor,  $C_2$ , by referring to the Bandwidth versus Input Signal Amplitude graph. If the input amplitude variation is known, the appropriate value of  $f_0 C_2$  necessary to give the desired bandwidth may be found. Conversely, an area of operation may be selected on this graph and the input level and  $C_2$  may be adjusted accordingly. For example, constant bandwidth operation requires that input amplitude be above 200mVrms. The bandwidth, as noted on the graph, is then controlled solely by the  $f_0 C_2$  product ( $F_0$  (Hz),  $C_2$  ( $\mu\text{fd}$ )).
3. The value of  $C_3$  is generally non-critical.  $C_3$  sets the band edge of a low pass filter which attenuates frequencies outside the detection band to eliminate spurious outputs. If  $C_3$  is too small, frequencies just outside the detection band will switch the output stage on and off at the beat frequency, or the output may pulse on and off during the turn-on transient. If  $C_3$  is too large, turn-on and turn-off of the output stage will be delayed until the voltage on  $C_3$  passes the threshold voltage. (Such a delay may be desirable to avoid spurious outputs due to transient frequencies.) A typical minimum value for  $C_3$  is  $2C_2$ .



**AVAILABLE OUTPUTS (Figure 2)**

The primary output is the uncommitted output transistor collector, pin 8. When an in-band input signal is present, this transistor saturates; its collector voltage being less than 1.0 volt (typically 0.6V) at full output current (100mA). The voltage at pin 2 is the phase detector output, a linear function of frequency, over the range of 0.95 to 1.05  $f_0$ , with a slope of about 20mV/% frequency deviation. The average voltage at pin 1 is, during lock, a function of the in-band input amplitude in accordance with the transfer characteristic given. Pin 5 is the controlled oscillator square wave output of magnitude  $(V^+ - 2V_{be}) \approx (V^+ - 1.4V)$  having a dc average of  $V^+/2$ . A 1K $\Omega$  load may be driven from pin 5. Pin 6 is an exponential triangle of 1 volt peak-to-peak

**AVAILABLE OUTPUTS (Cont'd.)**

with an average dc level of  $V^+ / 2$ . Only high impedance loads may be connected to pin 6 without affecting the CCO duty cycle or temperature stability.

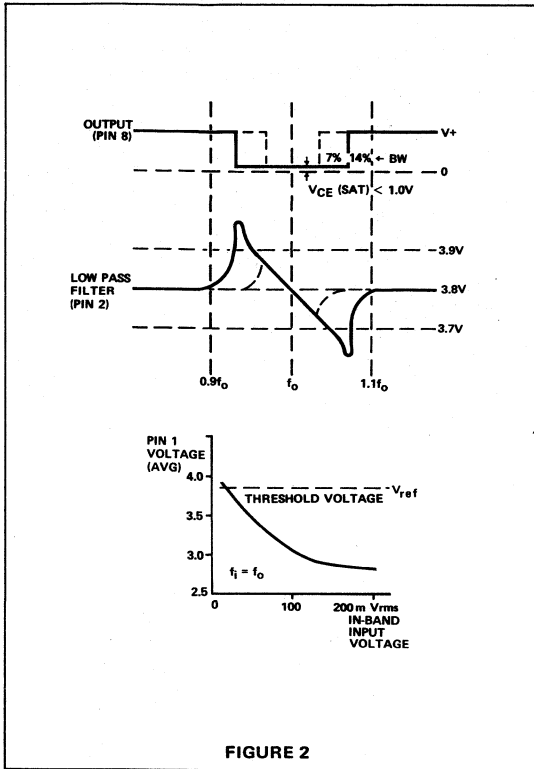


FIGURE 2

**OPERATING PRECAUTIONS**

A brief review of the following precautions will help the user attain the high level of performance of which the 567 is capable.

1. Operation in the high input level mode (above 200mV) will free the user from bandwidth variations due to changes in the in-band signal amplitude. The input stage is now limiting, however, so that out-band signals or high noise levels can cause an apparent bandwidth reduction as the in band signal is suppressed. Also, the limiting action will create in-band components from sub-harmonic signals, so the 567 becomes sensitive to signals at  $f_0/3$ ,  $f_0/5$ , etc.
2. The 567 will lock onto signals near  $(2n+1) f_0$ , and will give an output for signals near  $(4n+1) f_0$  where  $n = 0, 1, 2$ , etc. Thus, signals at  $5 f_0$  and  $9 f_0$  can cause an unwanted output. If such signals are anticipated, they should be attenuated before reaching the 567 input.
3. Maximum immunity from noise and out-band signals is afforded in the low input level (Below 200mVrms) and reduced bandwidth operating mode. However, decreased loop damping causes the worst-case lock-up time to increase, as shown by the Greatest Number of Cycles Before Output vs. Bandwidth graph.

4. Due to the high switching speeds (20ns) associated with 567 operation, care should be taken in lead routing. Lead lengths should be kept to a minimum. The power supply should be adequately bypassed close to the 567 with an  $0.01\mu F$  or greater capacitor; grounding paths should be carefully chosen to avoid ground loops and unwanted voltage variations. Another factor which must be considered is the effect of load energization on the power supply. For example, an incandescent lamp typically draws 10 times rated current at turn-on. This can cause supply voltage fluctuations which could, for example, shift the detection band of narrow-band systems sufficiently to cause momentary loss of lock. The result is a low-frequency oscillation into and out of lock. Such effects can be prevented by supplying heavy load currents from a separate supply, or increasing the supply filter capacitor.

**SPEED OF OPERATION**

Minimum lock-up time is related to the natural frequency of the loop. The lower it is, the longer becomes the turn-on transient. Thus, maximum operating speed is obtained when  $C_2$  is at a minimum. When the signal is first applied, the phase may be such as to initially drive the controlled oscillator away from the incoming frequency rather than toward it. Under this condition, which is of course unpredictable, the lock-up transient is at its worst and the theoretical minimum lock-up time is not achievable. We must simply wait for the transient to die out.

The following expressions give the values of  $C_2$  and  $C_3$  which allow highest operating speeds for various band center frequencies. The minimum rate at which digital information may be detected without information loss due to the turn-on transient or output chatter is about 10 cycles per bit, corresponding to an information transfer rate of  $f_0/10$  baud.

$$C_2 = \frac{130}{f_0} \mu F$$

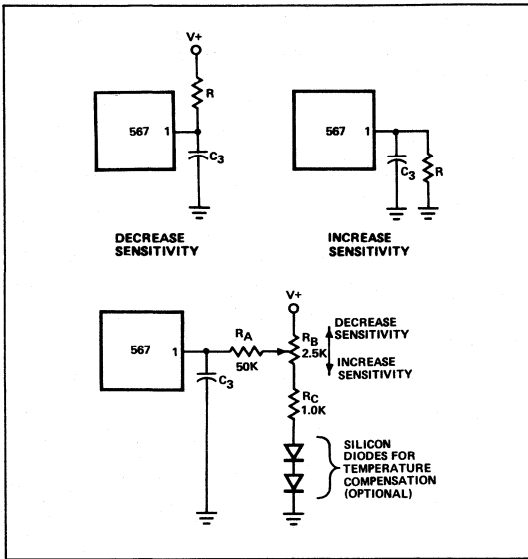
$$C_3 = \frac{260}{f_0} \mu F$$

in cases where turn-off time can be sacrificed to achieve fast turn-on, the optional sensitivity adjustment circuit can be used to move the quiescent  $C_3$  voltage lower (closer to the threshold voltage). However, sensitivity to beat frequencies, noise and extraneous signals will be increased.

**OPTIONAL CONTROLS**

The 567 has been designed so that, for most applications, no external adjustments are required. Certain applications, however, will be greatly facilitated if full advantage is taken of the added control possibilities available through the use of additional external components. In the diagrams given, typical values are suggested where applicable. For best results resistors used, except where noted, should have the same temperature coefficient. Ideally, silicon diodes would be low-resistivity types, such as forward-biased low-voltage zeners or forward-biased transistor base-emitter junctions. However, ordinary low-voltage diodes should be adequate for most applications.

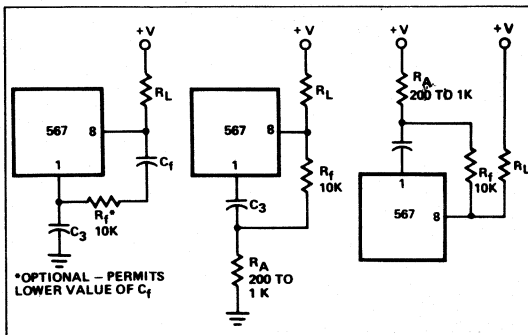
**SENSITIVITY ADJUSTMENT**



When operated as a very narrow band detector (less than 8 percent), both  $C_2$  and  $C_3$  are made quite large in order to improve noise and outband signal rejection. This will inevitably slow the response time. If, however, the output stage is biased closer to the threshold level, the turn-on time can be improved. This is accomplished by drawing additional current to terminal 1. Under this condition, the 567 will also give an output for lower-level signals (10m or lower).

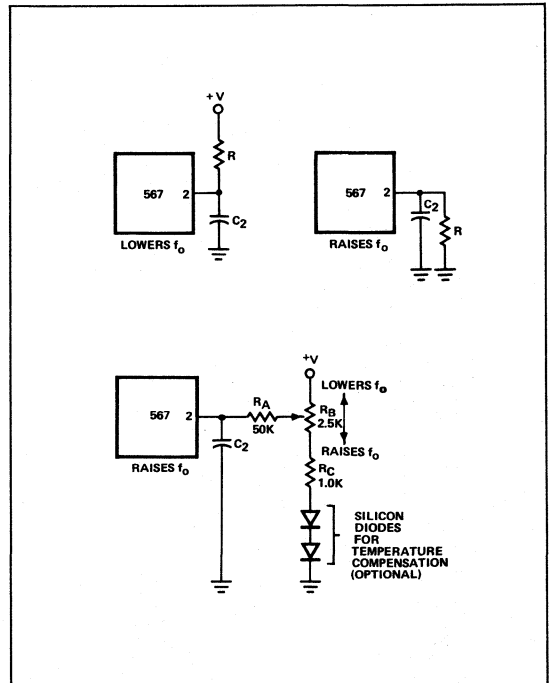
By adding current to terminal 1, the output stage is biased further away from the threshold voltage. This is most useful when, to obtain maximum operating speed,  $C_2$  and  $C_3$  are made very small. Normally, frequencies just outside the detection band could cause false outputs under this condition. By desensitizing the output stage, the outband beat notes do not feed through to the output stage. Since the input level must be somewhat greater when the output stage is made less sensitive, rejection of third harmonics or in-band harmonics (of lower frequency signals) is also improved.

**CHATTER PREVENTION**



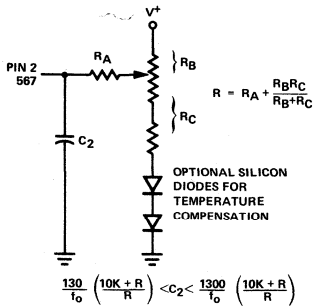
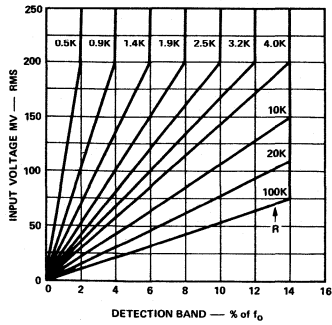
Chatter occurs in the output stage when  $C_3$  is relatively small, so that the lock transient and the AC components at the quadrature phase detector (lock detector) output cause the output stage to move through its threshold more than once. Many loads, for example lamps and relays, will not respond to the chatter. However, logic may recognize the chatter as a series of outputs. By feeding the output stage output back to its input, (pin 1) the chatter can be eliminated. Three schemes for doing this are given above. All operate by feeding the first output step (either on or off) back to the input, pushing the input past the threshold until the transient conditions are over. It is only necessary to assure that the feedback time constant is not so large as to prevent operation at the highest anticipated speed. Although chatter can always be eliminated by making  $C_3$  large, the feedback circuit will enable faster operation of the 567 by allowing  $C_3$  to be kept small. Note that if the feedback time constant is made quite large, a short burst at the input frequency can be stretched into a long output pulse. This may be useful to drive, for example, stepping relays.

**DETECTION BAND CENTERING (OR SKEW) ADJUSTMENT**



When it is desired to alter the location of the detection band (corresponding to the loop capture range) within the largest detection band (lock range), the circuits shown above can be used. By moving the detection band to one edge of the range, for example, input signal variations will expand the detection band in only one direction. This may prove useful when a strong but undesirable signal is expected on one side or the other of the center frequency. Since  $R_B$  also alters the duty cycle slightly, this method may be used to obtain a precise duty cycle when the 567 is used as an oscillator.

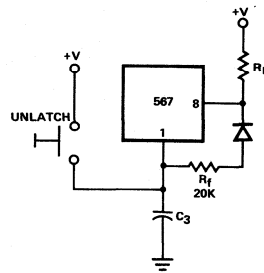
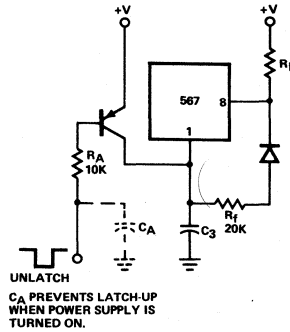
ALTERNATE METHOD OF BANDWIDTH REDUCTION



NOTE: Adjust control for symmetry of detection band edges about  $f_0$ .

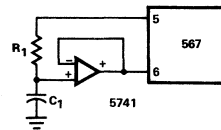
Although a large value of  $C_2$  will reduce the bandwidth, it also reduces the loop damping so as to slow the circuit response time. This may be undesirable. Bandwidth can be reduced by reducing the loop gain. This scheme will improve damping and permit faster operation under narrow-band operation. Note that the reduced impedance level at terminal 2 will require that a larger value of  $C_2$  be used for a given filter cutoff frequency. If more than three 567s are to be used, the  $R_B$ ,  $R_C$  network can be eliminated and the  $R_A$  resistors connected together. A capacitor between this junction and ground may be required to shunt high frequency components.

OUTPUT LATCHING



To latch the output on after a signal is received, it is necessary to provide a feedback resistor around the output stage (between pins 8 and 1). Pin 1 is pulled up to unlatch the output stage.

REDUCTION OF  $C_1$  VALUE



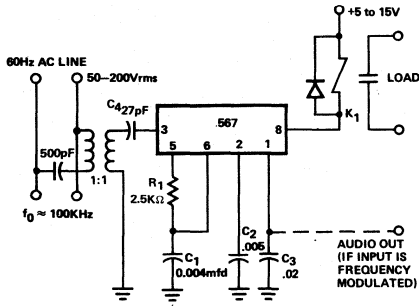
For precision, very low-frequency applications, where the value of  $C_1$  becomes large, an overall cost savings may be achieved by inserting a voltage follower between the  $R_1$   $C_1$  junction and pin 6, so as to allow a higher value of  $R_1$  and a lower value of  $C_1$  for a given frequency.

PROGRAMMING

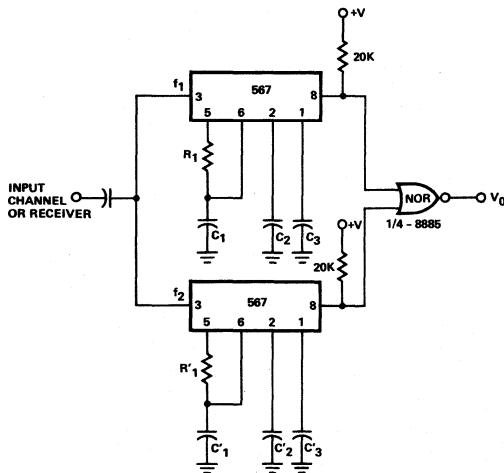
To change the center frequency, the value of  $R_1$  can be changed with a mechanical or solid state switch, or additional  $C_1$  capacitors may be added by grounding them through saturating npn transistors.

TYPICAL APPLICATIONS

CARRIER-CURRENT REMOTE CONTROL OR INTERCOM

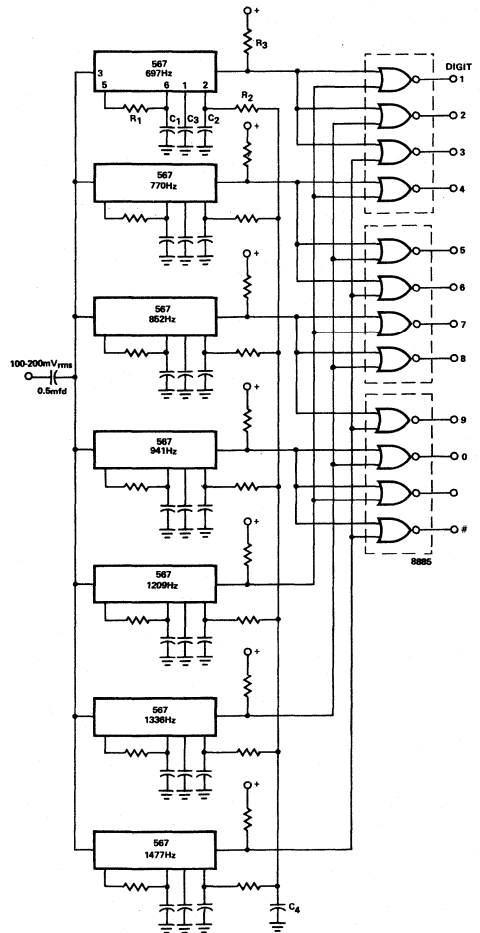


DUAL-TONE DECODER



1. Resistor and capacitor values chosen for desired frequencies and bandwidth.
2. If  $C_3$  is made large so as to delay turn-on of the top 567, decoding of sequential ( $f_1, f_2$ ) tones is possible.

TOUCH-TONE<sup>®</sup> DECODER



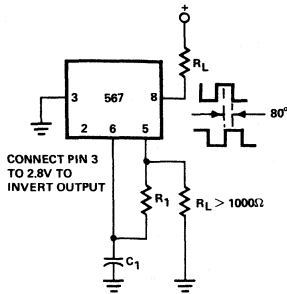
Component Values (Typical)

- $R_1$  6.8 to 15K ohm
- $R_2$  4.7K ohm
- $R_3$  20K ohm
- $C_1$  0.10 mfd
- $C_2$  1.0 mfd 6V
- $C_3$  2.2mfd 6V
- $C_4$  250 6V

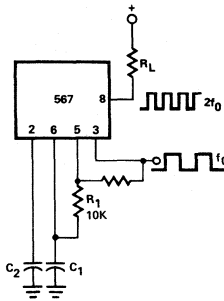


TYPICAL APPLICATIONS (Cont'd.)

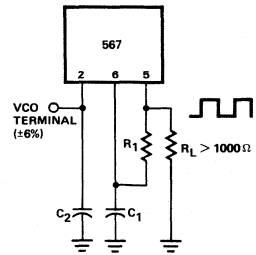
OSCILLATOR WITH QUADRATURE OUTPUT



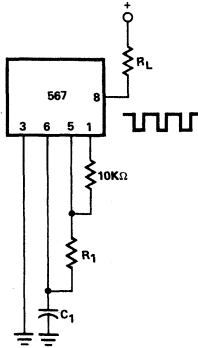
OSCILLATOR WITH DOUBLE FREQUENCY OUTPUT



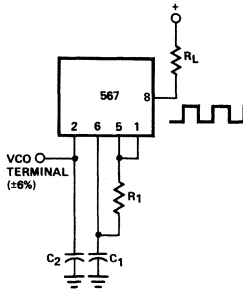
PRECISION OSCILLATOR WITH 20nsec SWITCHING



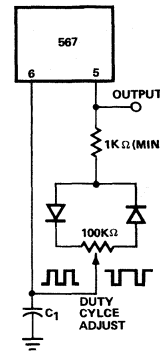
PULSE GENERATOR WITH 25% DUTY CYCLE



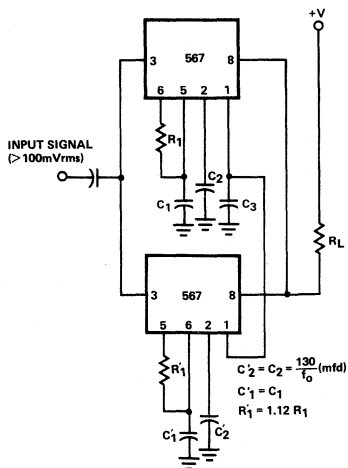
PRECISION OSCILLATOR TO SWITCH 100ma LOADS



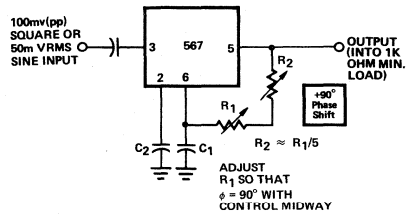
PULSE GENERATOR



24% BANDWIDTH TONE DECODER



0° TO 180° PHASE SHIFTER



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The SE/NE 592 is a monolithic, two stage, differential output, wideband video amplifier. It offers fixed gains of 100 and 400 without external components and adjustable gains from 400 to 0 with one external resistor. The input stage has been designed so that with the addition of a few external reactive elements between the gain select terminals, the circuit can function as a high pass, low pass, or band pass filter. This feature makes the circuit ideal for use as a video or pulse amplifier in communications, magnetic memories, display and video recorder systems. The 592 is a pin-for-pin replacement for the  $\mu A733$ .

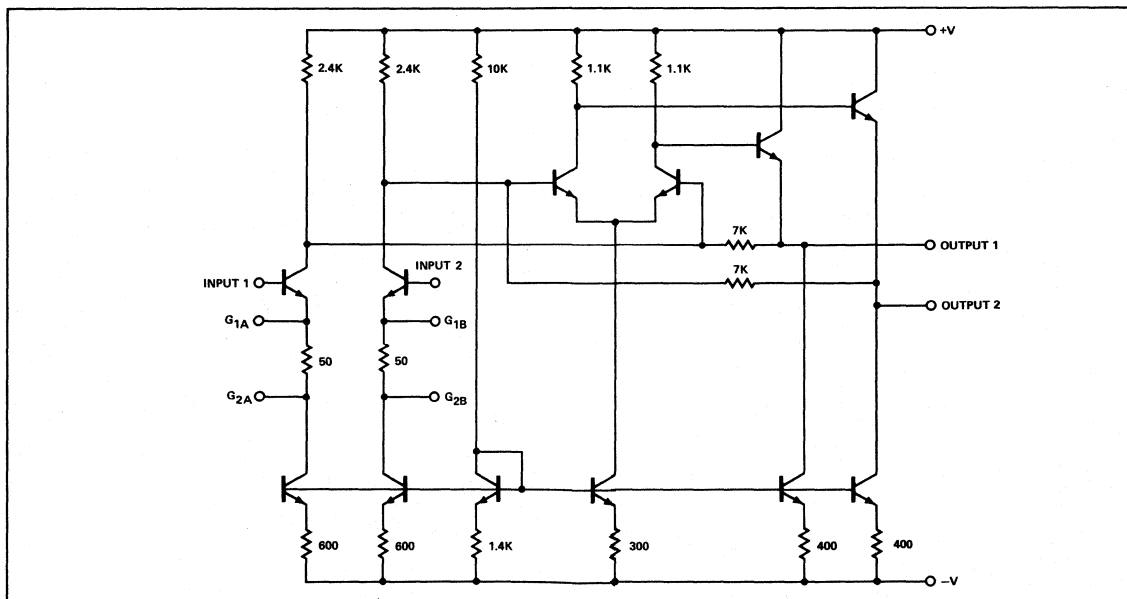
### FEATURES

- 120 MHz BANDWIDTH
- ADJUSTABLE GAINS FROM 0 TO 400
- ADJUSTABLE PASS BAND
- NO FREQUENCY COMPENSATION REQUIRED

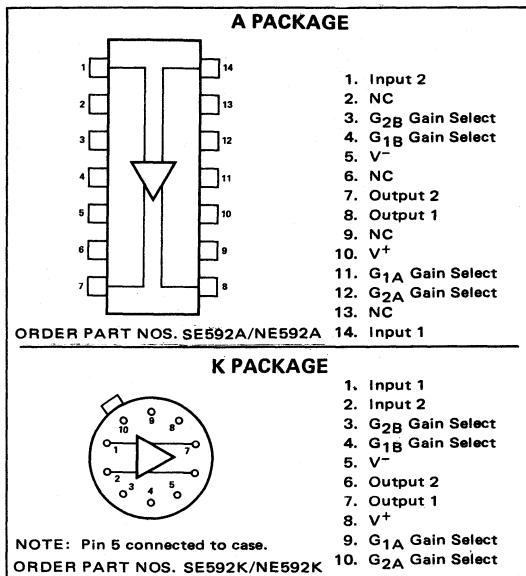
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	$\pm 8V$
Differential Input Voltage	$\pm 5V$
Common Mode Input Voltage	$\pm 6V$
Output Current	10mA
Operating Temperature Range	
SE592K	$-55^{\circ}C$ to $+125^{\circ}C$
NE592K	$0^{\circ}C$ to $+70^{\circ}C$
Storage Temperature Range	$-65^{\circ}C$ to $+150^{\circ}C$

### EQUIVALENT CIRCUIT



### PIN CONFIGURATIONS (Top View)



Thermal Resistance ( $\theta_{JA}$ , Junction to Ambient for each package):  
 A Package 0.16 $^{\circ}C/mW$   
 K Package 0.145 $^{\circ}C/mW$   
 Power Dissipation 500mW

ELECTRICAL CHARACTERISTICS Standard Conditions ( $T_A = +25^{\circ}\text{C}$ ,  $V_S = \pm 6\text{V}$ ,  $V_{CM} = 0$  unless otherwise specified)

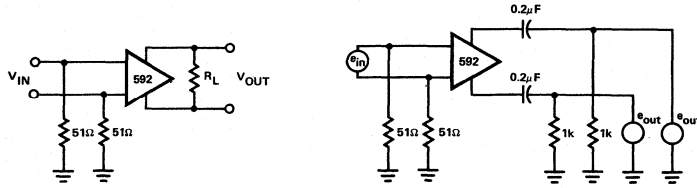
PARAMETER	TEST CONDITIONS	NE 592			SE 592			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Differential Voltage Gain								
Gain 1	Note 1	250	400	600	300	400	500	
Gain 2	$R_L = 2\text{K}\Omega$ , $V_{OUT} = 3\text{V p-p}$							
Bandwidth	Note 2	80	100	120	90	100	110	
Gain 1	Note 1		40			40		MHz
Gain 2	Note 2		90			90		MHz
Rise Time								
Gain 1	Note 1		10.5			10.5		ns
Gain 2	$V_{OUT} = 1\text{V p-p}$		4.5	12		4.5	10	ns
Propagation Delay	Note 2							
Gain 1	Note 1		7.5			7.5		ns
Gain 2	$V_{OUT} = 1\text{V p-p}$		6.0	10		6.0	10	ns
Input Resistance	Note 2							
Gain 1	Note 1		4.0			4.0		$\text{K}\Omega$
Gain 2	Note 2	10	30		20	30		$\text{K}\Omega$
Input Capacitance	Gain 2, Note 2		2.0			2.0		pF
Input Offset Current			0.4	5.0		0.4	3.0	$\mu\text{A}$
Input Bias Current			9.0	30		9.0	20	$\mu\text{A}$
Input Noise Voltage	BW 1 kHz to 10 kHz		12			12		$\mu\text{V rms}$
Input Voltage Range				$\pm 1.0$			$\pm 1.0$	V
Common Mode Rejection Ratio								
Gain 2	$V_{CM} \pm 1\text{V}$ , $F < 100\text{ kHz}$	60	86		60	86		dB
Gain 2	$V_{CM} \pm 1\text{V}$ , $F = 5\text{ MHz}$		60			60		dB
Supply Voltage Rejection Ratio								
Gain 2	$\Delta V_S = \pm 0.5\text{V}$	50	70		50	70		dB
Output Offset Voltage								
Gain 3	$R_L = \infty$ , Note 3		0.35	0.75		0.35	0.75	V
Output Common Mode Voltage	$R_L = \infty$	2.4	2.9	3.4	2.4	2.9	3.4	V
Output Voltage Swing	$R_L = 2\text{K}$	3.0	4.0		3.0	4.0		
Output Resistance			20			20		$\Omega$
Power Supply Current	$R_L = \infty$		18	24		18	24	mA

Recommended Operating Supply Voltages ( $V_S = \pm 6.0\text{V}$ )

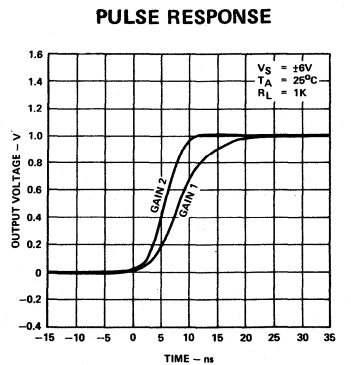
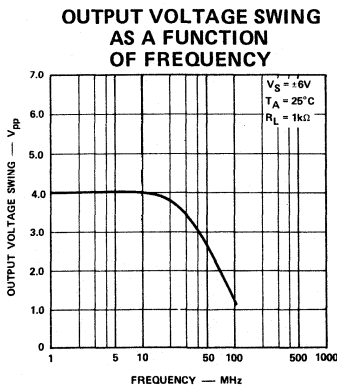
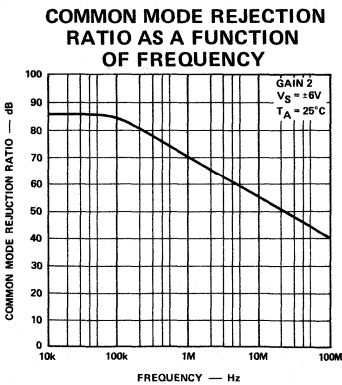
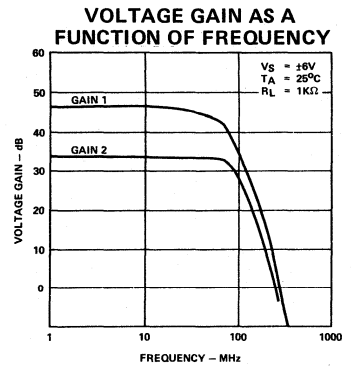
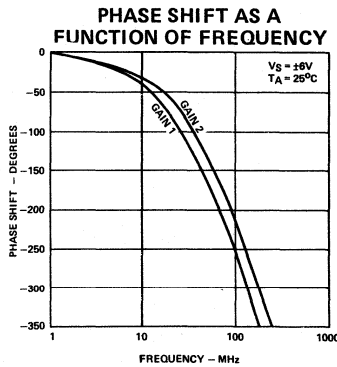
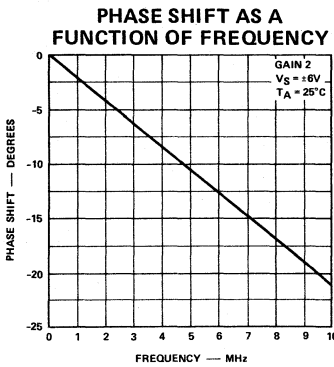
NOTES:

1. Gain select pins  $G_{1A}$  and  $G_{1B}$  connected together.
2. Gain select pins  $G_{2A}$  and  $G_{2B}$  connected together.
3. All gain select pins open.

TEST CIRCUITS ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

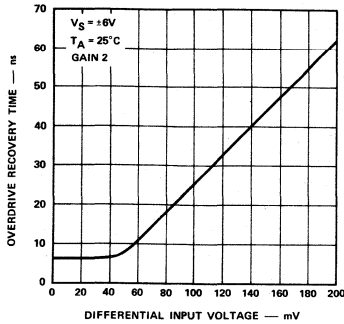


TYPICAL CHARACTERISTICS

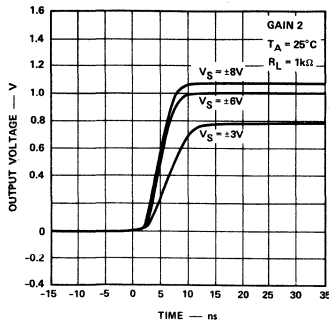


TYPICAL CHARACTERISTIC CURVES (Cont'd)

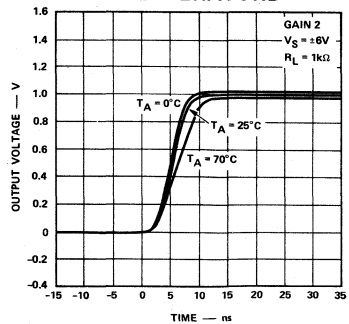
**DIFFERENTIAL OVERDRIVE RECOVERY TIME**



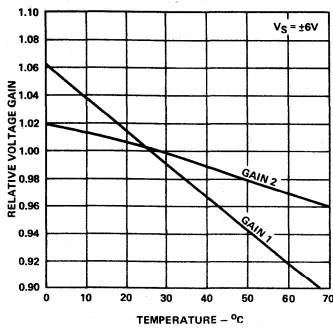
**PULSE RESPONSE AS A FUNCTION OF SUPPLY VOLTAGE**



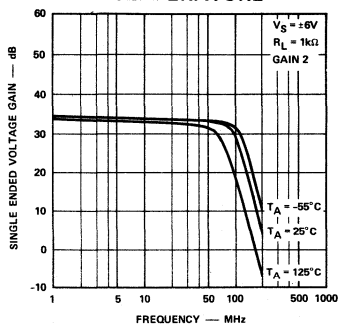
**PULSE RESPONSE AS A FUNCTION OF TEMPERATURE**



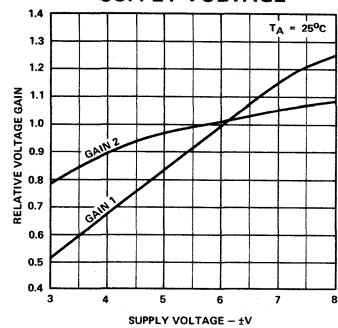
**VOLTAGE GAIN AS A FUNCTION OF TEMPERATURE**



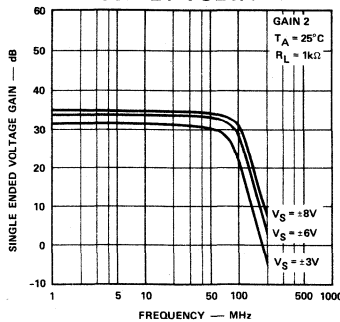
**GAIN VS FREQUENCY AS A FUNCTION OF TEMPERATURE**



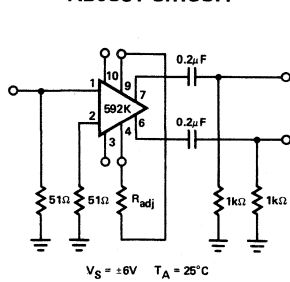
**VOLTAGE GAIN AS A FUNCTION OF SUPPLY VOLTAGE**



**GAIN VS FREQUENCY AS A FUNCTION OF SUPPLY VOLTAGE**



**VOLTAGE GAIN ADJUST CIRCUIT**



(Pin numbers apply to K Package)

**VOLTAGE GAIN AS A FUNCTION OF RADJ (FIGURE 3)**

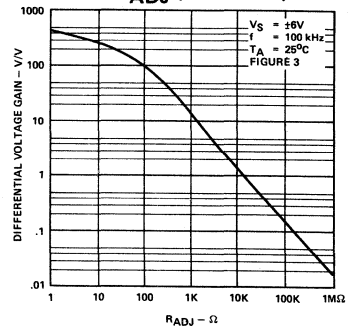
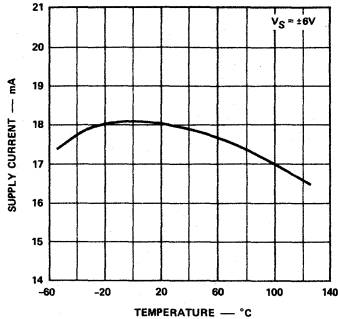


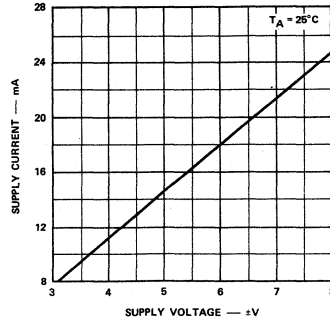
FIGURE 3

TYPICAL CHARACTERISTIC CURVES (Cont'd)

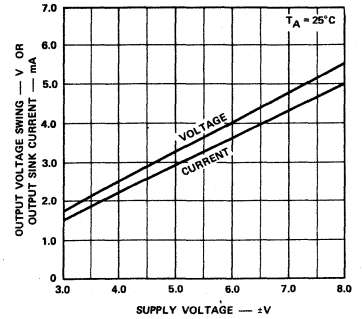
**SUPPLY CURRENT AS A FUNCTION OF TEMPERATURE**



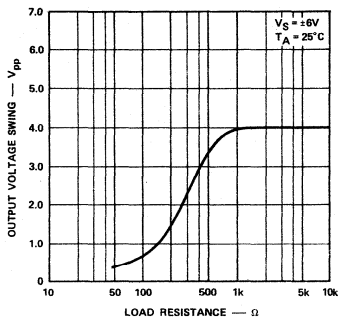
**SUPPLY CURRENT AS A FUNCTION OF SUPPLY VOLTAGE**



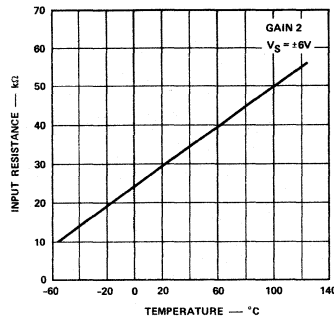
**OUTPUT VOLTAGE AND CURRENT SWING AS A FUNCTION OF SUPPLY VOLTAGE**



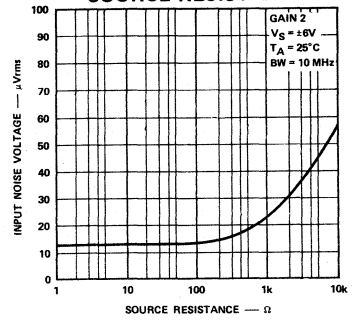
**OUTPUT VOLTAGE SWING AS A FUNCTION OF LOAD RESISTANCE**



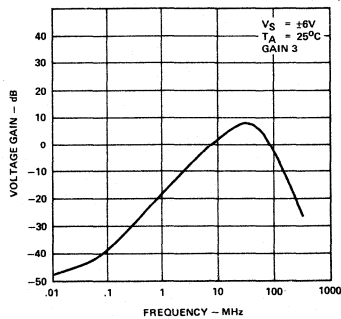
**INPUT RESISTANCE AS A FUNCTION OF TEMPERATURE**



**INPUT NOISE VOLTAGE AS A FUNCTION OF SOURCE RESISTANCE**

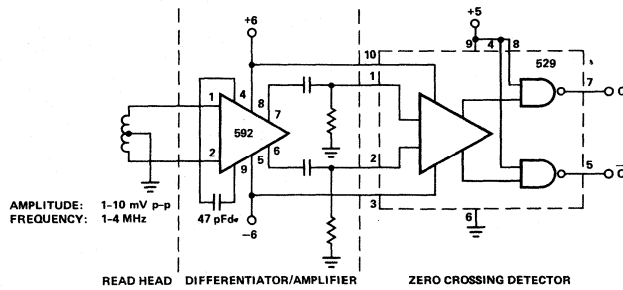


**VOLTAGE GAIN AS A FUNCTION OF FREQUENCY (ALL GAIN SELECT PINS OPEN)**

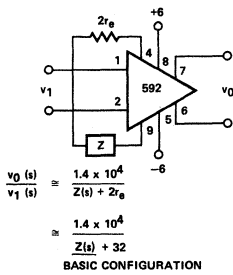


TYPICAL APPLICATIONS

DISC/TAPE PHASE MODULATED  
READBACK SYSTEMS



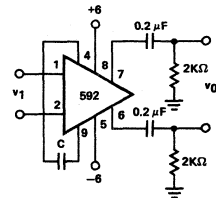
FILTER NETWORKS



Z NETWORK	FILTER TYPE	$\frac{v_0(s)}{v_1(s)}$ TRANSFER FUNCTION
	LOW PASS	$\frac{1.4 \times 10^4}{L} \left[ \frac{1}{s + R/L} \right]$
	HIGH PASS	$\frac{1.4 \times 10^4}{R} \left[ \frac{s}{s + 1/RC} \right]$
	BAND PASS	$\frac{1.4 \times 10^4}{L} \left[ \frac{s}{s^2 + R/L s + 1/LC} \right]$
	BAND REJECT	$\frac{1.4 \times 10^4}{R} \left[ \frac{s^2 + 1/LC}{s^2 + 1/LC + s/RC} \right]$

NOTE: IN THE NETWORKS ABOVE, THE R VALUE USED IS ASSUMED TO INCLUDE  $2r_e$ , OR APPROXIMATELY 32 OHMS.

DIFFERENTIATION WITH  
HIGH COMMON MODE  
NOISE REJECTION

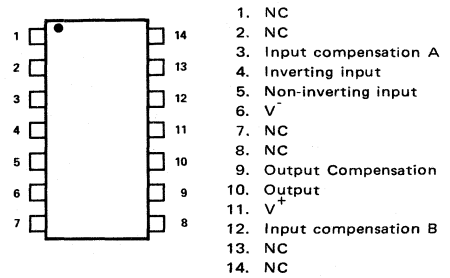


FOR FREQUENCY  $F_1 \ll 1/2\pi(32)C$   
 $v_0 \approx 1.4 \times 10^4 C \frac{dv_1}{dt}$

## LINEAR INTEGRATED CIRCUITS

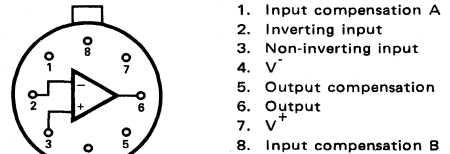
### PIN CONFIGURATIONS (TOP VIEW)

#### A PACKAGE



ORDER PART NOS.  
 $\mu$ A790A/ $\mu$ A709CA

#### T PACKAGE



ORDER PART NOS.  $\mu$ A709T/ $\mu$ A709CT

### DESCRIPTION

The  $\mu$ A709 is a high performance monolithic operational amplifier with differential inputs. High open loop gain, high input impedance, wide input common mode and output voltage ranges plus low temperature drift enable it to be used in many applications formerly satisfied only by discrete amplifiers.

### FEATURES

- OPEN LOOP VOLTAGE GAIN = 45,000
- OUTPUT VOLTAGE SWING =  $\pm 14V$
- INPUT COMMON MODE RANGE =  $\pm 10V$
- DIFFERENTIAL INPUT RESISTANCE =  $\mu$ A709 250k $\Omega$   
 $\mu$ A709C 400k $\Omega$

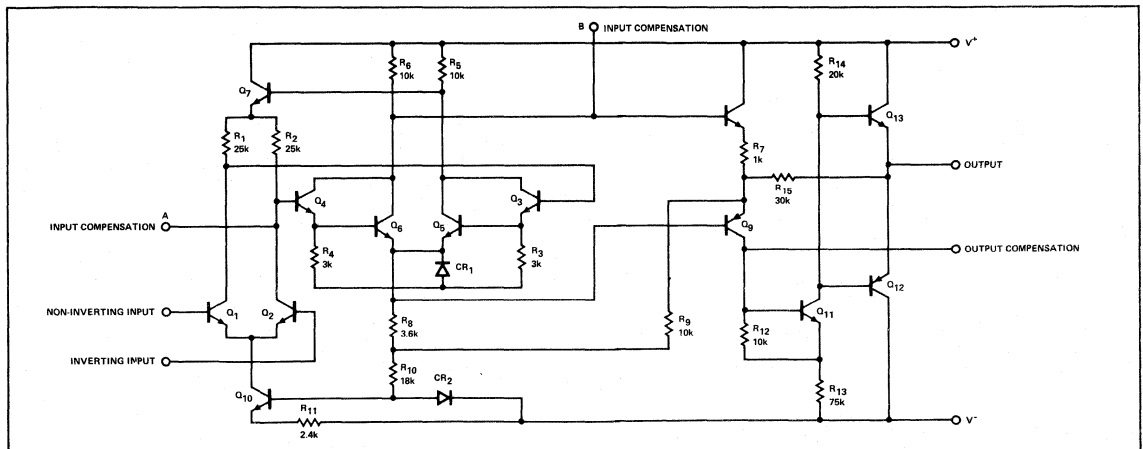
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	$\pm 18V$
Internal Power Dissipation (Note 1)	N5709 250 mW S5709 300 mW
Differential Input Voltage	$\pm 5.0V$
Input Voltage	$\pm 10V$
Open Short-Circuit Duration ( $T_A = 25^\circ C$ )	$-25^\circ C$
Storage Temperature Range	$-65^\circ C$ to $+150^\circ C$
Operating Temperature Range	$\mu$ A709C $0^\circ C$ to $+75^\circ C$ $\mu$ A709 $-55^\circ C$ to $+125^\circ C$
Lead Temperature (Soldering, 60 sec)	$300^\circ C$

#### NOTE:

1. Rating applied for case temperatures to  $+125^\circ C$ ; derate linearly at 5.6mW/ $^\circ C$  for ambient temperatures above  $+95^\circ C$ .

### BASIC CIRCUIT SCHEMATIC

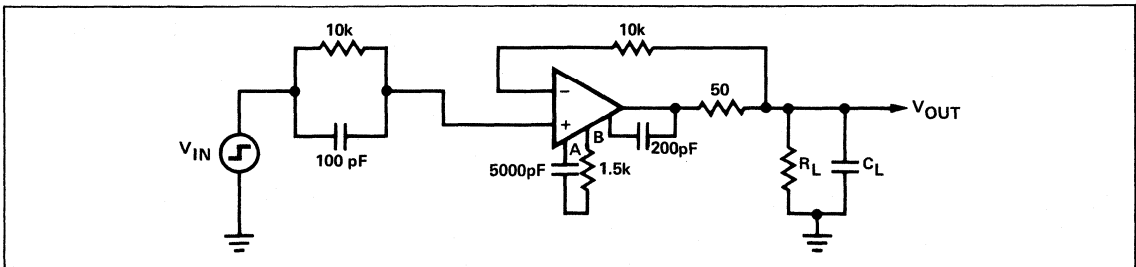




ELECTRICAL CHARACTERISTICS ( $T_A = \pm 25^\circ\text{C}$ ,  $V_S = \pm 15\text{V}$  (709C);  $\pm 9 \leq V_S \leq \pm 15$  (709) unless otherwise specified)

PARAMETER	TEST CONDITIONS	$\mu A709$			$\mu A709\text{C}$			UNITS
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
INPUT CHARACTERISTICS	$R_S \leq 10\text{K}\Omega$ , $+9\text{V} \leq V_S \leq +15\text{V}$		1	5		2	7.5	mV
		Offset Voltage @ $25^\circ\text{C}$						
Over Temperature	$R_S \leq 10\text{K}\Omega$ , $\pm 9\text{V} \leq \pm 15\text{V}$			6			10	mV
Offset Current @ $25^\circ\text{C}$	$T_A = +125^\circ\text{C}$		50	200		100	500	nA
		Over Temperature		20	200			
Bias Current @ $25^\circ\text{C}$	$T_A = -55^\circ\text{C}$		100	500				nA
		Over Temperature						750
INPUT RESISTANCE @ $25^\circ\text{C}$	$0^\circ\text{C} \leq T_A \leq 75^\circ\text{C}$		200	500		300	1500	nA
		Over Temperature		0.5	1.5			
INPUT VOLTAGE RANGE @ $25^\circ\text{C}$	$T_A = -55^\circ\text{C}$		150	400	50	250		$\text{k}\Omega$
		Over Temperature		40	100	35		
OUTPUT CHARACTERISTICS	$V_S = \pm 15\text{V}$		$\pm 8.0$	$\pm 10$	$\pm 8.0$	$\pm 10$		V
		Resistance @ $25^\circ\text{C}$						
Voltage Swing	$R_L \geq 10\text{K}\Omega$				$\pm 12$	$\pm 14$		V
		Over Temperature				$\pm 10$	$\pm 13$	
POWER CONSUMPTION	$V_S = \pm 15\text{V}$ , $R_L \geq 10\text{K}\Omega$		$\pm 10$	$\pm 13$				V
		Over Temperature						
TRANSIENT RESPONSE	$V_S = \pm 15\text{V}$ , $R_L \geq 2\text{K}\Omega$		80	165		80	200	mW
		Over Temperature						
LARGE SIGNAL VOLTAGE GAIN @ $25^\circ\text{C}$	$V_{in} = 10\text{mV}$ , $R_L = 2\text{K}\Omega$		0.3	1.0	0.3			$\mu\text{S}$
		Over Temperature		10	30	10	30	
COMMON MODE REJECTION RATIO @ $25^\circ\text{C}$	$C_L \leq 100\text{pF}$				15,000	45,000		V/V
		Over Temperature				12,000		
SUPPLY VOLTAGE REJECTION RATIO @ $25^\circ\text{C}$	$R_L \geq 25\text{K}\Omega$ , $V_{out} = \pm 10\text{V}$		25,000	45,000	70,000	12,000		V/V
		Over Temperature						
AVERAGE TEMPERATURE	$R_S \leq 10\text{K}\Omega$		70	90	65	90		dB
		Over Temperature						
COEFFICIENT OF INPUT	$R_S \leq 10\text{K}\Omega$					25	200	$\mu\text{V}/\text{V}$
		Over Temperature						
OFFSET VOLTAGE	$R_S \leq 10\text{K}\Omega$		25	150				$\mu\text{V}/^\circ\text{C}$
		Over Temperature						

TEST CIRCUIT



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The  $\mu A710$  is a High Speed Differential Voltage Comparator featuring low offset voltage, high sensitivity and a wide input voltage range. It is ideally suited for use as a pulse height discriminator, an analog comparator or a digital line receiver. The output structure of the  $\mu A710$  is compatible with DTL, TTL and Utilogic integrated circuits.

The  $\mu A710$  is specified for operation over the MIL temperature range of  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ . The  $\mu A710\text{C}$  is specified for operation over the commercial/industrial temperature range of  $0^{\circ}\text{C}$  to  $+75^{\circ}\text{C}$ .

### FEATURES

- FAST RESPONSE — 40ns
- HIGH SENSITIVITY — 1.7V/mv
- LOW OFFSET VOLTAGE TEMPERATURE COEFFICIENT —  $3.5\mu\text{V}/^{\circ}\text{C}$
- HIGH INPUT VOLTAGE RANGE —  $\pm 5.0\text{V}$

### ABSOLUTE MAXIMUM RATINGS

Positive Supply Voltage	+14.0V
Negative Supply Voltage	-7.0V
Peak Output Current	10mA
Differential Input Voltage	$\pm 5.0\text{V}$
Input Voltage	$\pm 7.0\text{V}$
Internal Power Dissipation (Note 4)	
TO-99	300mW
TO-91	200mW

### Operating Temperature Range

$\mu A710$	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
$\mu A710\text{C}$	$0^{\circ}\text{C}$ to $+75^{\circ}\text{C}$

### Storage Temperature Range

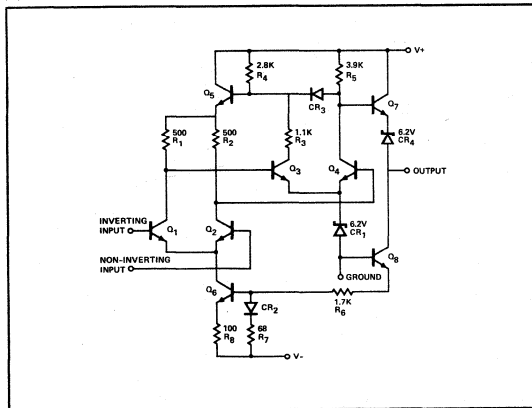
$-65^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$

### Lead Temperature (Soldering, 60 sec)

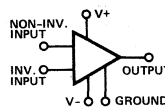
$300^{\circ}\text{C}$

Maximum Ratings are limiting values above which serviceability may be impaired.

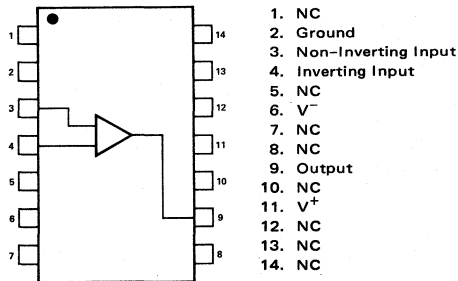
### BASIC CIRCUIT SCHEMATIC



### PIN CONFIGURATION (TOP VIEW)

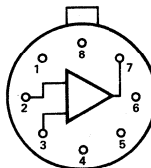


### A PACKAGE



ORDER PART NOS.  $\mu A710\text{A}/\mu A710\text{CA}$

### T PACKAGE



ORDER PART NOS.  $\mu A710\text{T}/\mu A710\text{CT}$

# SIGNETICS DIFFERENTIAL VOLTAGE COMPARATOR ■ $\mu$ A710

## ELECTRICAL CHARACTERISTICS (Note 1)

(Standard Conditions:  $T_A = +25^\circ\text{C}$ ,  $V^+ = 12\text{V}$ ,  $V^- = -6.0\text{V}$  unless otherwise specified)

PARAMETERS	TEST CONDITIONS	MIN		TYP		MAX		UNITS
		$\mu$ A710	$\mu$ A710C	$\mu$ A710	$\mu$ A710C	$\mu$ A710	$\mu$ A710C	
Input Offset Voltage	$R_S \leq 200\Omega$ Note 3			0.6	1.6	2.0	5.0	mV
Input Offset Current	Note 3			0.75	1.8	3.0	5.0	$\mu\text{A}$
Input Bias Current				13	16	20	25	$\mu\text{A}$
Voltage Gain		1250	1000	1700	1500			
Output Resistance				200	200			$\Omega$
Output Sink Current	$\Delta V_{in} \geq 5\text{mV}$ , $V_{out} = 0$	2.0	1.6	2.5				mA
Response Time	Note 2			40	40			ns
Except as noted, the following specifications apply over the temperature ranges of: $-55^\circ\text{C} \leq T_A \leq +125^\circ\text{C}$ for the S5710 $0^\circ\text{C} \leq T_A \leq +75^\circ\text{C}$ for the N5710								
Input Offset Voltage	$R_S \leq 200\Omega$ Note 3					3.0	6.5	
Average Temperature Coefficient of Input Offset Voltage	$R_S = 50\Omega$ , $T_A = +25^\circ\text{C}$ to $+125^\circ\text{C}$ $R_S = 50\Omega$ , $T_A = +25^\circ\text{C}$ to $-55^\circ\text{C}$ $R_S = 50\Omega$ , $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$			3.5		10		$\mu\text{V}/^\circ\text{C}$
Input Offset Current	$T_A = +125^\circ\text{C}$ Note 3 $T_A = -55^\circ\text{C}$ $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$			0.25		3.0		$\mu\text{A}$
Average Temperature Coefficient of Input Offset Current	$T_A = +25^\circ\text{C}$ to $+125^\circ\text{C}$ $T_A = +25^\circ\text{C}$ to $-55^\circ\text{C}$ $T_A = +25^\circ\text{C}$ to $+75^\circ\text{C}$ $T_A = +25^\circ\text{C}$ to $0^\circ\text{C}$			5.0		25		nA/ $^\circ\text{C}$
Input Bias Current	$T_A = -55^\circ\text{C}$ $T_A = 0^\circ\text{C}$			15		75		nA/ $^\circ\text{C}$
Input Common Mode Voltage Range	$V^- = -7.0\text{V}$	$\pm 5.0$	$\pm 5.0$					V
Common Mode Rejection Ratio	$R_S \leq 200\Omega$	80	70	100	98			dB
Differential Input Voltage Range		$\pm 5.0$	$\pm 5.0$					
Voltage Gain		1000	800					
Positive Output Level	$\Delta V_{in} \geq 5\text{mV}$ , $0 \leq I_{out} \leq 5.0\text{mA}$	2.5	2.5	3.2	3.2	4.0	4.0	V
Negative Output Level	$\Delta V_{in} \geq 5\text{mV}$	-1.0	-1.0	-0.5	-0.5	0	0	V
Output Sink Current	$T_A = +125^\circ\text{C}$ , $\Delta V_{in} \geq 5\text{mV}$ , $V_{out} = 0$ $T_A = -55^\circ\text{C}$ , $\Delta V_{in} \geq 5\text{mV}$ , $V_{out} = 0$ $T_A = 0^\circ\text{C}$ to $+75^\circ\text{C}$ , $\Delta V_{in} \geq 5\text{mV}$ , $V_{out} = 0$	0.5		1.7				mA
Positive Supply Current	$V_{out} \leq 0$		0.5	2.3				mA
Negative Supply Current				5.2	5.2	9.0	9.0	mA
Power Consumption				4.6	4.6	7.0	7.0	mA
				90	90	150	150	mW

(Recommended Operating Supply Voltages:  $V^+ = 12\text{V}$ ,  $V^- = -6\text{V}$ )

**NOTES:**

- All voltages are referenced to pin F.
- The response time specified is measured with a 100mV input step, and a 5mV overdrive.
- Input Offset Voltage and Input Offset Current are specified for output voltage levels of:

$\mu$ A710	$\mu$ A710C
1.8V at $-55^\circ\text{C}$	1.5V at $0^\circ\text{C}$
1.4V at $+25^\circ\text{C}$	1.4V at $+25^\circ\text{C}$
1.0V at $+125^\circ\text{C}$	1.2V at $+75^\circ\text{C}$

- Rating applies for temperatures up to:  $\mu$ A710 -  $+125^\circ\text{C}$   
 $\mu$ A710C -  $+75^\circ\text{C}$

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The  $\mu$ A711 High Speed Dual Voltage Comparator features low offset voltage, high sensitivity and a wide input voltage range. It is ideal for use as a bi-directional limit detector in automatic test equipment.

Due to fast response and strobe control capabilities the  $\mu$ A711 performs well as a sense amplifier in core memory systems.

The  $\mu$ A711 is specified over the military temperature range of  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ . The  $\mu$ A711 is specified over the commercial/industrial temperature range of  $0^{\circ}\text{C}$  to  $+75^{\circ}\text{C}$ .

### FEATURES

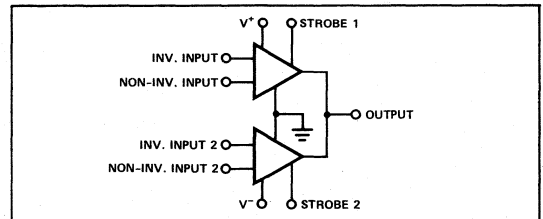
- FAST RESPONSE – 40ns
- HIGH SENSITIVITY – 1.5V/mV
- LOW OFFSET VOLTAGE TEMPERATURE COEFFICIENT –  $5\mu\text{V}/^{\circ}\text{C}$
- HIGH INPUT VOLTAGE RANGE –  $\pm 5.0\text{V}$

### ABSOLUTE MAXIMUM RATINGS

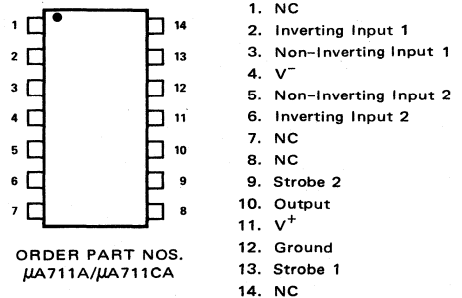
Positive Supply Voltage	+14.0V
Negative Supply Voltage	-7.0V
Peak Output Current	50mA
Differential Input Voltage	$\pm 5.0\text{V}$
Input Voltage	$\pm 7.0\text{V}$
Internal Power Dissipation (Note 4)	
TO-99	300mW
Operating Temperature Range	
$\mu$ A711	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
$\mu$ A711C	$0^{\circ}\text{C}$ to $+75^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Lead Temperature (Soldering, 60 sec)	$300^{\circ}\text{C}$

Maximum ratings are limiting values above which serviceability may be impaired.

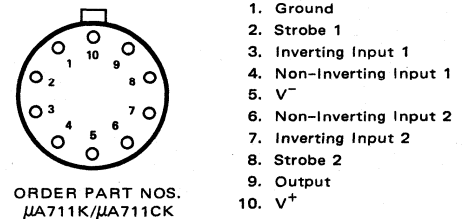
### PIN CONFIGURATION (Top View)



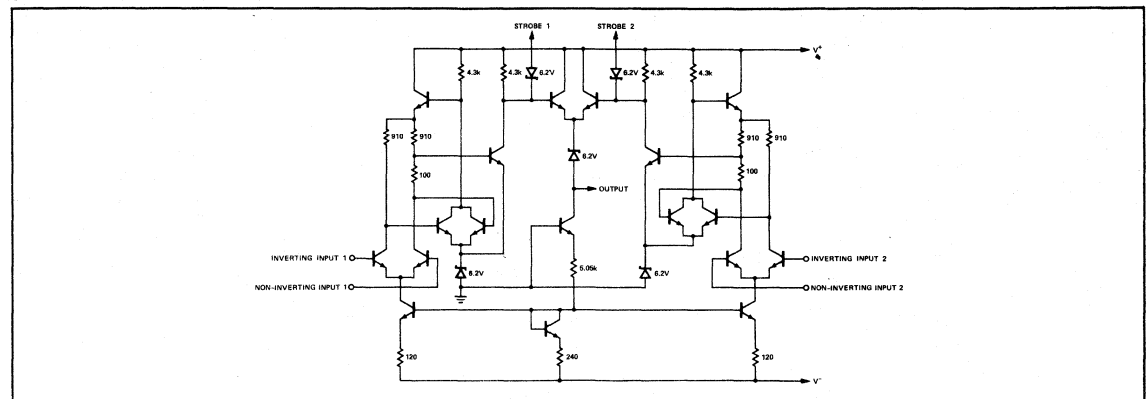
#### A PACKAGE



#### K PACKAGE



### BASIC CIRCUIT SCHEMATIC



**ELECTRICAL CHARACTERISTICS** (Note 1)

(Standard Conditions:  $T_A = +25^\circ C$ ,  $V^+ = 12.0V$ ,  $V^- = -6.0V$  unless otherwise specified)

PARAMETERS	TEST CONDITIONS	MIN		TYP		MAX		UNITS
		$\mu A711$	711C	$\mu A711$	711C	$\mu A711$	711C	
Input Offset Voltage	$V_{out} = +1.4V$ , $R_S \leq 200\Omega$ , $V_{cm} = 0$			1.0	1.0	3.5	5.0	mV
	$V_{out} = +1.4V$ , $R_S \leq 200\Omega$			1.0	1.0	5.0	7.5	mV
Input Offset Current	$V_{out} = +1.4V$			0.5	0.5	10.0	15.0	$\mu A$
Input Bias Current				25	25	75	100	$\mu A$
Voltage Gain		750	700	1500	1500			
Response Time	Note 2			40	40			ns
Strobe Release Time				12	12			ns
Input Common Mode Voltage Range	$V^- = -7.0V$	$\pm 5.0$	$\pm 5.0$					V
Differential Input Voltage Range		$\pm 5.0$	$\pm 5.0$					V
Output Resistance				200	200			$\Omega$
Positive Output Level	$V_{in} \geq 10mV$			4.5	4.5	5.0	5.0	V
Loaded Positive Output Level	$V_{in} \geq 10mV$ , $I_o = 5mA$	2.5	2.5	3.5	3.5			V
Negative Output Level	$V_{in} \geq 10mV$	-1.0	-1.0	-0.5	-0.5	0	0	V
Strobed Output Level	$V_{strobe} < 0.3V$	-1.0	-1.0			0	0	V
Output Sink Current	$V_{in} \geq 10mV$ , $V_{out} \geq 0$	0.5	0.5	0.8	0.8			mA
Strobe Current	$V_{strobe} = 100mV$			1.2	1.2	2.5	2.5	mA
Positive Supply Current	$V_{out} \leq 0$			8.6	8.6			mA
Negative Supply Current				3.9	3.9			mA
Power Consumption				130	130	200	200	mW

The following specifications apply over the temperature ranges of:  $-55^\circ C \leq T_A \leq +125^\circ C$  for the  $\mu A711$   
 $0^\circ C \leq T_A \leq +75^\circ C$  for the  $\mu A711C$

Input Offset Voltage	$R_S \leq 200\Omega$ , $V_{cm} = 0$ , $R_S \leq 200\Omega$	Note 3				4.5	6.0	mV
Input Offset Current		Note 3				6.0	10.0	mV
Input Bias Current						20	25	$\mu A$
Temperature Coefficient of Input Offset Voltage				5.0	5.0	150	150	$\mu A$
Voltage Gain			500	500				$\mu V/^\circ C$

Recommended Operating Supply Voltages:  $V^+ = 12V$ ,  $V^- = -6V$

NOTES:

- All voltages are referenced to pin 1.
- The response time specified is for a 100mV input step, with a 5mV overdrive.
- The Input Offset Voltage and Input Offset Current are specified for a logic threshold voltage of: 1.8V at  $0^\circ C$ .
 

$\mu A711$	$\mu A711C$
1.8V at $0^\circ C$	1.5V at $0^\circ C$
1.4V at $+25^\circ C$	1.4V at $+25^\circ C$
1.0V at $+125^\circ C$	1.2V at $+75^\circ C$
- Rating applies for temperatures up to:  $\mu A711 - +125^\circ C$   
 $\mu A711C - +75^\circ C$

## LINEAR INTEGRATED CIRCUITS

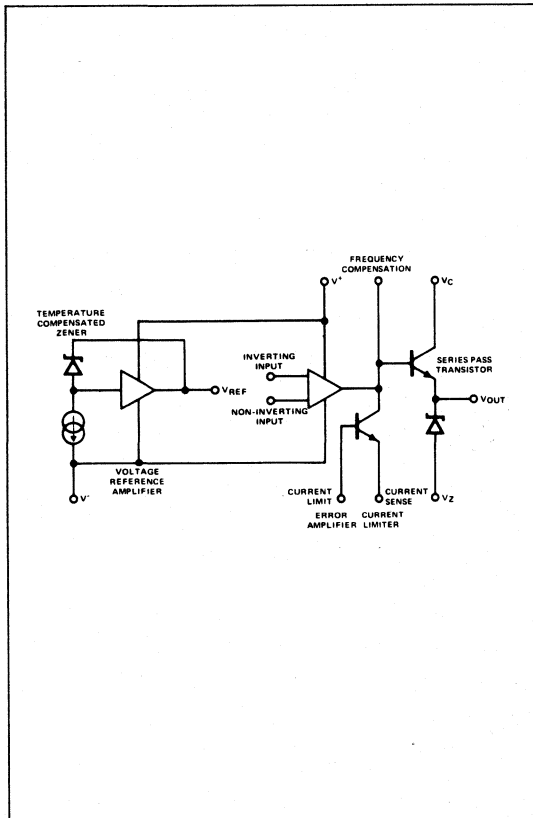
### DESCRIPTION

The  $\mu$ A723 is a Monolithic Precision Voltage Regulator capable of operation in positive or negative supplies as a series, shunt, switching or floating regulator. The  $\mu$ A723 contains a temperature compensated reference amplifier, error amplifier, series pass transistor, and current limiter, with access to remote shutdown.

### FEATURES

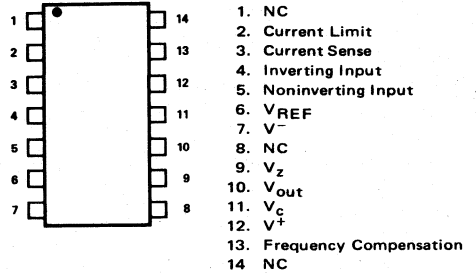
- POSITIVE OR NEGATIVE SUPPLY OPERATION
- SERIES, SHUNT, SWITCHING OR FLOATING OPERATION
- .01% LINE AND LOAD REGULATION
- OUTPUT VOLTAGE ADJUSTABLE FROM 2 TO 37 VOLTS
- OUTPUT CURRENT TO 150mA WITHOUT EXTERNAL PASS TRANSISTOR

### EQUIVALENT CIRCUIT



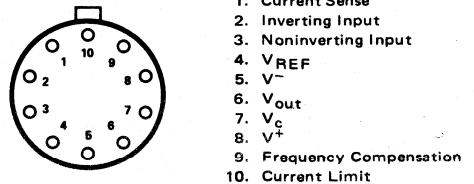
### PIN CONFIGURATION (Top View)

#### A PACKAGE



ORDER PART NOS.  $\mu$ A723A/ $\mu$ A723CA

#### L PACKAGE



ORDER PART NOS.  $\mu$ A723L/ $\mu$ A723CL

### ABSOLUTE MAXIMUM RATINGS

	$\mu$ A723	$\mu$ A723C
Pulse Voltage from V <sup>+</sup> to V <sup>-</sup> (50ms)	50V	
Continuous Voltage from V <sup>+</sup> to V <sup>-</sup>	40V	40V
Input-Output Voltage Differential	40V	40V
Maximum Output Current	150mA	150mA
Current from V <sub>REF</sub>	15mA	
Current from V <sub>Z</sub>		25mA
Internal Power Dissipation (Note 1)	800mW	800mW
Operating Temperature Range	-55 to +125°C	0 to 70°C
Storage Temperature Range	-65°C to +150°C	-65°C to +150°C
Lead Temperature	300°C	300°C

# SIGNETICS PRECISION VOLTAGE REGULATOR ■ $\mu$ A723

## ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25°C unless otherwise specified – Note 1)

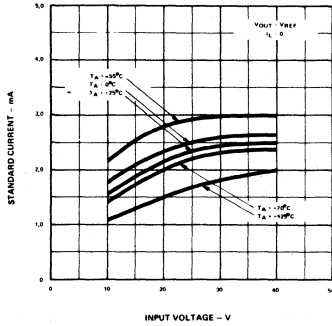
PARAMETER (See definitions)	MIN	TYP	MAX	UNITS	CONDITIONS
<b><math>\mu</math>A723C</b>					
Line Regulation (Note 2)		0.01 0.1	0.1 0.5	% V <sub>out</sub> % V <sub>out</sub>	V <sub>in</sub> = 12V to V <sub>in</sub> = 15V V <sub>in</sub> = 12V to V <sub>in</sub> = 40V
Load Regulation (Note 2)		0.03	0.2	% V <sub>out</sub>	I <sub>L</sub> = 1mA to I <sub>L</sub> = 50mA
Ripple Rejection		74 86		dB dB	f = 50 Hz to 10 kHz, C <sub>REF</sub> = 0 f = 50 Hz to 10 kHz, C <sub>REF</sub> = 5 $\mu$ F
Short Circuit Current Limit		65		mA	R <sub>sc</sub> = 10 $\Omega$ , V <sub>out</sub> = 0
Reference Voltage	6.80	7.15	7.50	V	
Output Noise Voltage		20 2.5		$\mu$ V rms $\mu$ V rms	BW = 100 Hz to 10 kHz, C <sub>REF</sub> = 0 BW = 100 Hz to 10 kHz, C <sub>REF</sub> = 5 $\mu$ F
Long Term Stability		0.1	0.1	%/1000 hrs.	
Standby Current Drain		2.3	4.0	mA	I <sub>L</sub> = 0, V <sub>in</sub> = 30V
Input Voltage Range	9.5		40	V	
Output Voltage Range	2.0		37	V	
Input-Output Voltage Differential	3.0		38	V	
The Following Specifications Apply Over the Operating Temperature Ranges					
Line Regulation			0.3	% V <sub>out</sub>	
Load Regulation			0.6	% V <sub>out</sub>	
Average Temperature Coefficient of Output Voltage		0.003	0.015	%/°C	V <sub>in</sub> = 12V to V <sub>in</sub> = 15V I <sub>L</sub> = 1mA to I <sub>L</sub> = 50mA
<b><math>\mu</math>A723</b>					
Line Regulation (Note 2)		0.01 0.02	0.1 0.2	%V <sub>out</sub> %V <sub>out</sub>	V <sub>in</sub> = 12V to V <sub>in</sub> = 15V V <sub>in</sub> = 12V to V <sub>in</sub> = 40V
Load Regulation (Note 2)		0.03	0.15	%V <sub>out</sub>	I <sub>L</sub> = 1mA to I <sub>L</sub> = 50mA
Ripple Rejection		74 86		dB dB	f = 50 Hz to 10 kHz, C <sub>REF</sub> = 0 f = 50 Hz to 10 kHz, C <sub>REF</sub> = 5 $\mu$ F
Short Circuit Current Limit		65		mA	R <sub>SC</sub> = 10 $\Omega$ , V <sub>out</sub> = 0
Reference Voltage	6.95	7.15	7.35	V	
Output Noise Voltage		20 2.5		$\mu$ V rms $\mu$ V rms	BW = 100 Hz to 10 kHz, C <sub>REF</sub> = 0 BW = 100 Hz to 10 kHz, C <sub>REF</sub> = 5 $\mu$ F
Long Term Stability		0.1		%/1000 hrs	
Standby Current Drain		2.3	3.5	mA	I <sub>L</sub> = 0, V <sub>in</sub> = 30V
Input Voltage Range	9.5		40	V	
Output Voltage Range	2.0		37	V	
Input-Output Voltage Differential	3.0		38	V	
The Following Specifications Apply Over the Operating Temperature Ranges					
Line Regulation			0.3	% V <sub>out</sub>	
Load Regulation			0.6	% V <sub>out</sub>	
Average Temperature Coefficient of Output Voltage		0.002	0.015	%/°C	V <sub>in</sub> = 12V to V <sub>in</sub> = 15V I <sub>L</sub> = 1mA to I <sub>L</sub> = 50mA

### NOTES

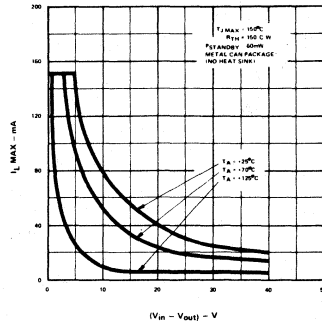
1. Unless otherwise specified, T<sub>A</sub> = 25°C, V<sub>in</sub> = V<sub>+</sub> = V<sub>c</sub> = 12V, V<sub>-</sub> = 0V, V<sub>out</sub> = 5V, I<sub>L</sub> = 1mA, R<sub>sc</sub> = 0, C<sub>1</sub> = 100pF, C<sub>REF</sub> = 0 and divider impedance as seen by error amplifier < 10k $\Omega$  when connected as shown in Figure 3.
2. The load and line regulation specifications are for constant junction temperature. Temperature drift effects must be taken into account separately when the unit is operating under conditions of high dissipation.

TYPICAL CHARACTERISTIC CURVES

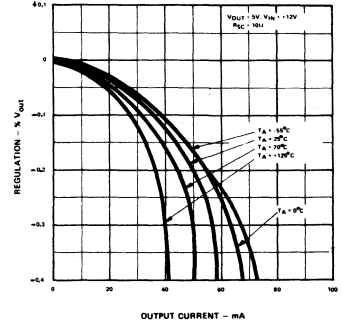
STANDBY CURRENT DRAIN AS A FUNCTION OF INPUT VOLTAGE



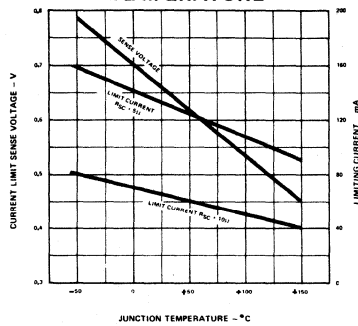
MAXIMUM LOAD CURRENT AS A FUNCTION OF INPUT-OUTPUT VOLTAGE DIFFERENTIAL



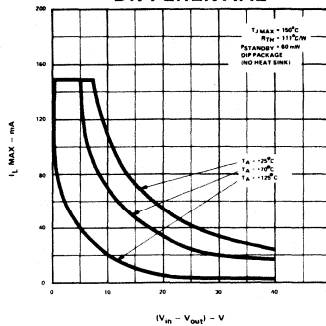
LOAD REGULATION CHARACTERISTICS WITH CURRENT LIMITING



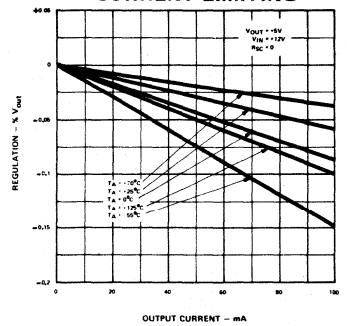
CURRENT LIMITING CHARACTERISTICS AS A FUNCTION OF JUNCTION TEMPERATURE



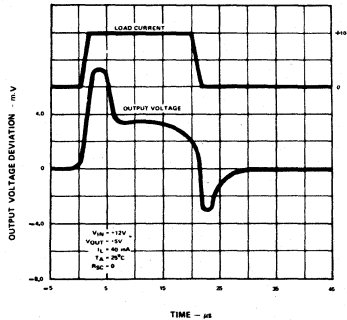
MAXIMUM LOAD CURRENT AS A FUNCTION OF INPUT-OUTPUT VOLTAGE DIFFERENTIAL



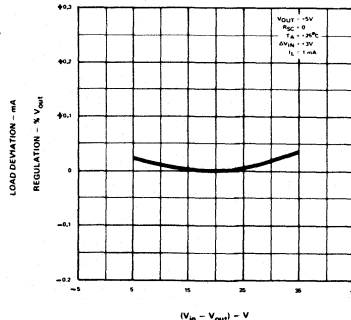
LOAD REGULATION CHARACTERISTICS WITHOUT CURRENT LIMITING



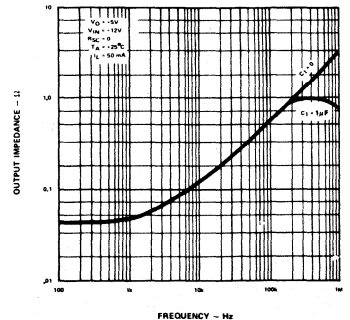
LOAD TRANSIENT RESPONSE



LINE REGULATION AS A FUNCTION OF INPUT-OUTPUT VOLTAGE DIFFERENTIAL

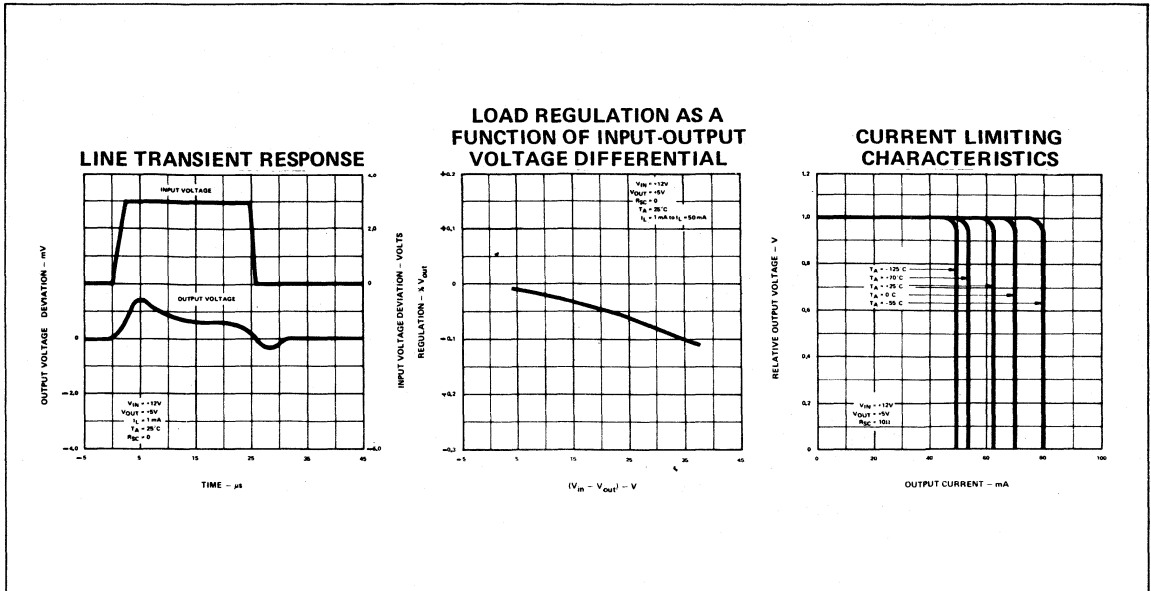


OUTPUT IMPEDANCE AS A FUNCTION OF FREQUENCY



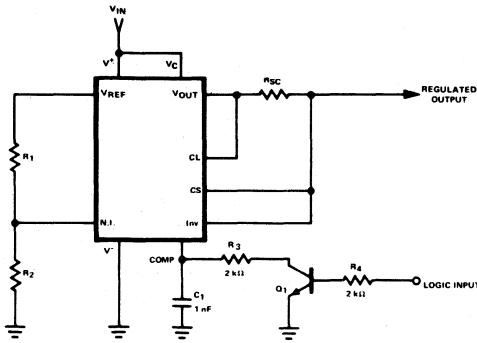


TYPICAL CHARACTERISTIC CURVES (Cont'd.)



BASIC  $\mu A723$  REGULATOR APPLICATIONS

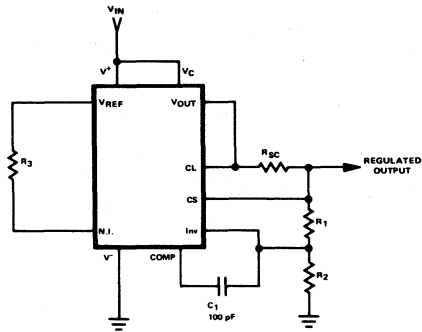
REMOTE SHUTDOWN REGULATOR WITH CURRENT LIMITING (V<sub>out</sub> = 2 to 7 Volts)



$$V_{out} = \left[ V_{REF} \times \frac{R_2}{R_1 + R_2} \right]$$

FIGURE 1

HIGH VOLTAGE REGULATOR (V<sub>out</sub> = 7 to 37 Volts)



$$V_{out} = \left[ V_{REF} \times \frac{R_1 + R_2}{R_2} \right]$$

$$R_3 = \frac{R_1 R_2}{R_1 + R_2} \text{ for minimum temperature drift}$$

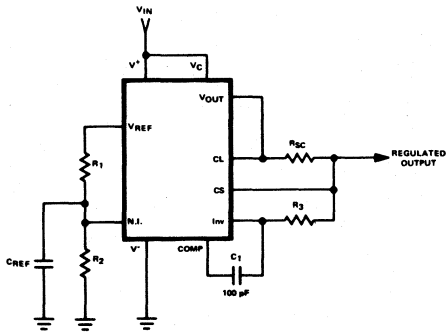
R<sub>3</sub> may be eliminated for minimum component count

FIGURE 2

# SIGNETICS PRECISION VOLTAGE REGULATOR ■ $\mu A723$

## BASIC $\mu A723$ REGULATOR APPLICATIONS (Cont'd.)

### LOW VOLTAGE REGULATOR ( $V_{out} = 2$ to 7 Volts)

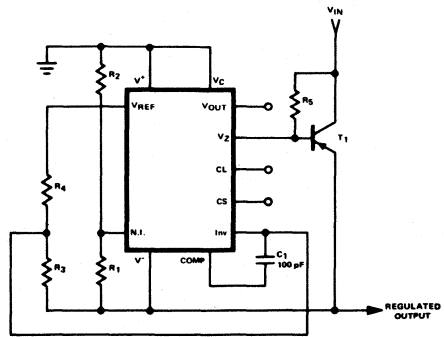


$$V_{out} = \left[ V_{REF} \times \frac{R_2}{R_1 + R_2} \right]$$

$$R_3 = \frac{R_1 R_2}{R_2 + R_2} \text{ for minimum temperature drift}$$

FIGURE 3

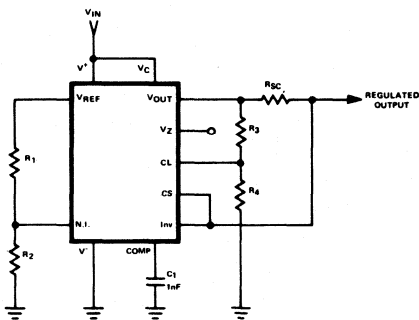
### NEGATIVE VOLTAGE REGULATOR



$$V_{out} = \left[ \frac{V_{REF}}{2} \times \frac{R_1 + R_2}{R_1} \right] ; R_3 = R_4$$

FIGURE 4

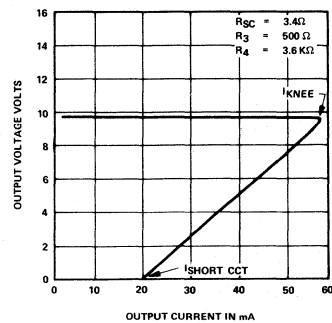
### FOLDBACK CURRENT LIMITING REGULATOR ( $V_{out} = 2$ to 7 Volts)



$$I_{KNEE} = \left[ \frac{V_{out} R_3}{R_{sc} R_4} + \frac{V_{SENSE} (R_3 + R_4)}{R_{sc} R_4} \right]$$

$$V_{out} = \left[ V_{REF} \times \frac{R_1 + R_2}{R_2} \right]$$

$$I_{SHORT\ CKT} = \left[ \frac{V_{SENSE}}{R_{sc}} \times \frac{R_3 + R_4}{R_4} \right]$$



$$\frac{R_4}{R_3} = \frac{V_{OUT} I_{SC}}{V_{SENSE} (I_{KNEE} - I_{SHORTCKT})} - 1$$

$$R_{SC} = \frac{V_{SENSE}}{I_{SC}} \left[ 1 + \frac{R_3}{R_4} \right]$$

FIGURE 5

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 733 is a monolithic differential input, differential output, wideband video amplifier. It offers fixed gains of 10, 100 or 400 without external components, and adjustable gains from 10 to 400 by the use of an external resistor. No external frequency compensation components are required for any gain option. Gain stability, wide bandwidth and low phase distortion are obtained through use of the classic series-shunt feedback from the emitter follower outputs to the inputs of the second stage. The emitter follower outputs provide low output impedance, and enable the device to drive capacitive loads. The 733 is intended for use as a high performance video and pulse amplifier in communications, magnetic memories, display and video recorder systems.

### FEATURES

- 120 MHz BANDWIDTH
- 250k $\Omega$  INPUT RESISTANCE
- SELECTABLE GAINS OF 10, 100 and 400
- NO FREQUENCY COMPENSATION REQUIRED

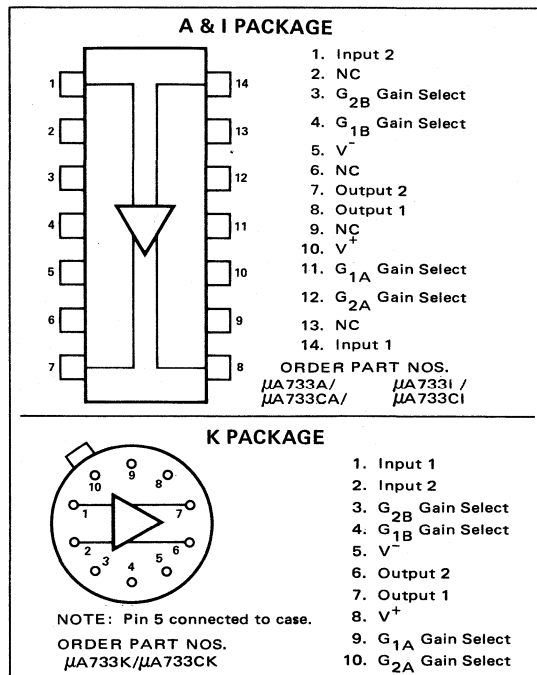
### ABSOLUTE MAXIMUM RATINGS

Differential Input Voltage	$\pm 5V$
Common Mode Input Voltage	$\pm 6V$
$V_{CC}$	$\pm 8V$

Output Current	10mA
Junction Temperature	+150 $^{\circ}C$
Storage Temperature Range	-65 $^{\circ}C$ to +150 $^{\circ}C$
Operation Temperature Range	

$\mu$ A733C	0 $^{\circ}C$ to +75 $^{\circ}C$
$\mu$ A733	-55 $^{\circ}C$ to +75 $^{\circ}C$

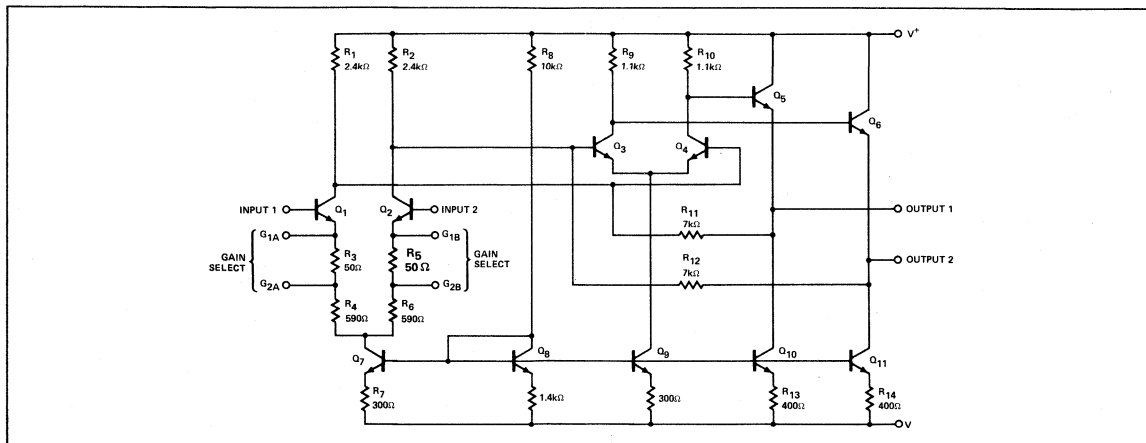
### PIN CONFIGURATIONS (Top View)



Thermal Resistance ( $\theta_{J-A}$ , Junction to Ambient for each package):

A Package	0.16 $^{\circ}C/mW$
I Package	0.10 $^{\circ}C/mW$
K Package	0.145 $^{\circ}C/mW$
Power Dissipation	500mW

### BASIC CIRCUIT SCHEMATIC



# SIGNETICS DIFFERENTIAL VIDEO AMPLIFIER ■ $\mu$ A733

## ELECTRICAL CHARACTERISTICS Standard Conditions ( $T_A = +25^\circ\text{C}$ , $V_S = \pm V$ , $V_{CM} = 0$ unless otherwise specified)

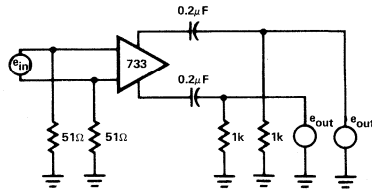
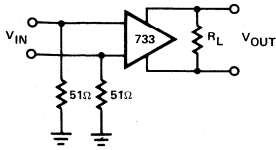
PARAMETERS	TEST CONDITIONS	$\mu$ A733C			$\mu$ A733			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Differential Voltage Gain								
Gain 1	Note 1	250	400	600	300	400	500	
Gain 2	$R_I = 2\text{k}\Omega$ , $V_{out} = 3V_{p-p}$ Note 2	80	100	120	90	100	110	
Gain 3	Note 3	8.0	10	12	9.0	10	11	
Bandwidth								
Gain 1	Note 1		40			40		MHz
Gain 2	Note 2		90			90		MHz
Gain 3	Note 3		120			120		MHz
Rise Time								
Gain 1	Note 1		10.5			10.5		ns
Gain 2	$V_{out} = 1V_{p-p}$ Note 2		4.5	12		4.5	10	ns
Gain 3	Note 3		2.5			2.5		ns
Propagation Delay								
Gain 1	Note 1		7.5			7.5		ns
Gain 2	$V_{out} = 1V_{p-p}$ Note 2		6.0	10		6.0	10	ns
Gain 3	Note 3		3.6			3.6		ns
Input Resistance								
Gain 1	Note 1		4.0			4.0		$\text{k}\Omega$
Gain 2	Note 2	10	30		20	30		$\text{k}\Omega$
Gain 3	Note 3		250			250		$\text{k}\Omega$
Input Capacitance	Gain 2 Note 2		2.0			2.0		pF
Input Offset Current			0.4	5.0		0.4	3.0	$\mu\text{A}$
Input Bias Current			9.0	30		9.0	20	$\mu\text{A}$
Input Noise Voltage	$BW = 1\text{ kHz to }10\text{ MHz}$		12			12		$\mu\text{V}_{rms}$
Input Voltage Range		$\pm 1.0$			$\pm 1.0$			V
Common Mode Rejection Ratio								
Gain 2	$V_{CM} = \pm 1V$ , $f \leq 100\text{ kHz}$	60	86		60	86		dB
Gain 2	$V_{CM} = \pm 1V$ , $F = 5\text{ MHz}$		60			60		dB
Supply Voltage Rejection Ratio								
Gain 2	$\Delta V_S = \pm 0.5V$	50	70		50	70		dB
Output Offset Voltage								
Gain 1	$R_L = \infty$ Note 1		0.6	1.5		0.6	1.5	V
Gain 2 and 3	Notes 2,3		0.35	1.5		0.35	1.0	V
Output Common Mode Voltage	$R_L = \infty$	2.4	2.9	3.4	2.4	2.9	3.4	V
Output Voltage Swing	$R_L = 2\text{k}$	3.0	4.0		3.0	4.0		
Output Sink Current		2.5	3.6		2.5	3.6		mA
Output Resistance			20			20		$\Omega$
Power Supply Current	$R_L = \infty$		18	24		18	24	mA

Recommended Operating Supply Voltages ( $V_S = \pm 6.0V$ )

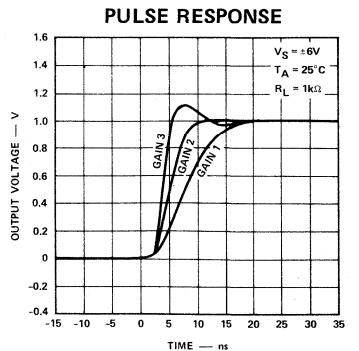
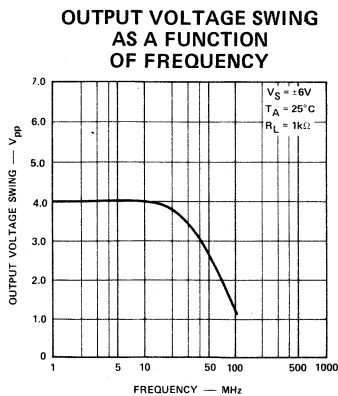
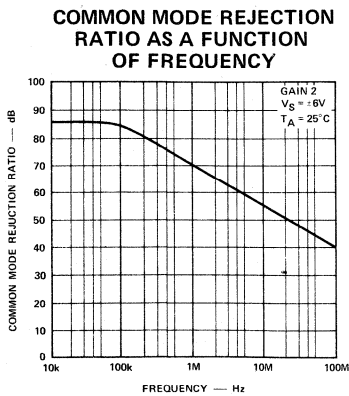
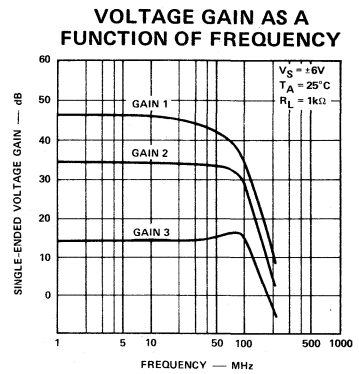
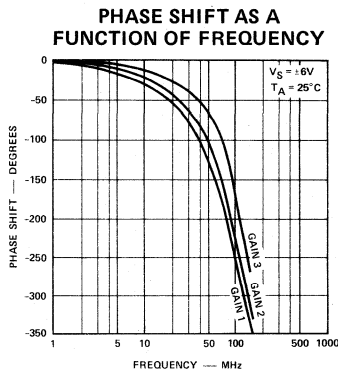
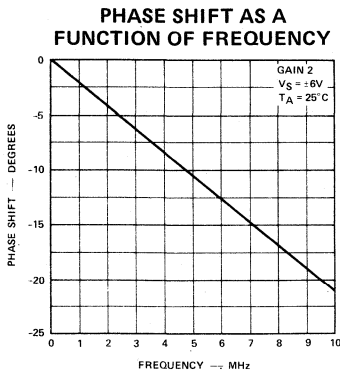
### NOTES

- Gain select pins  $G_{1A}$  and  $G_{1B}$  connected together.
- Gain select pins  $G_{2A}$  and  $G_{2B}$  connected together.
- All gain select pins open.

TEST CIRCUITS ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

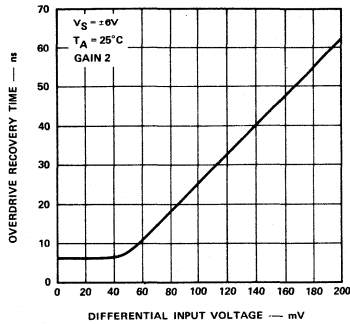


TYPICAL CHARACTERISTIC CURVES

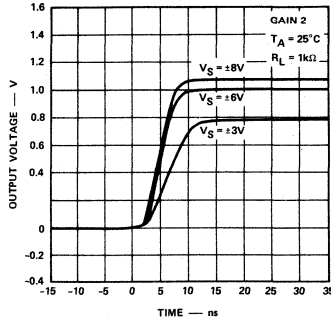


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

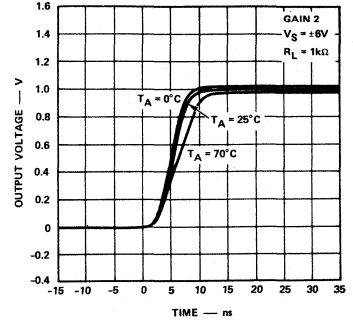
**DIFFERENTIAL OVERDRIVE RECOVERY TIME**



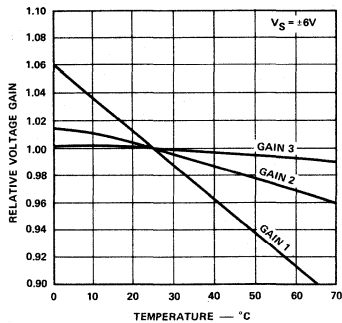
**PULSE RESPONSE AS A FUNCTION OF SUPPLY VOLTAGE**



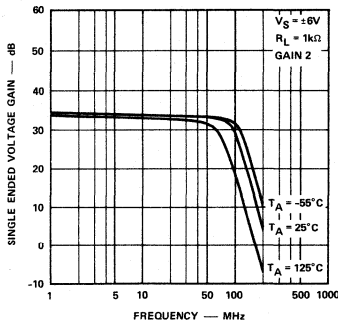
**PULSE RESPONSE AS A FUNCTION OF TEMPERATURE**



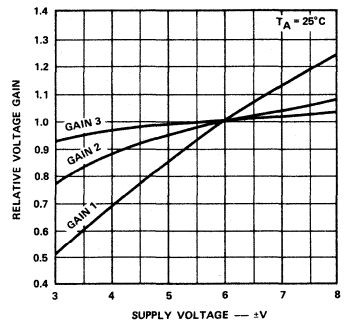
**VOLTAGE GAIN AS A FUNCTION OF TEMPERATURE**



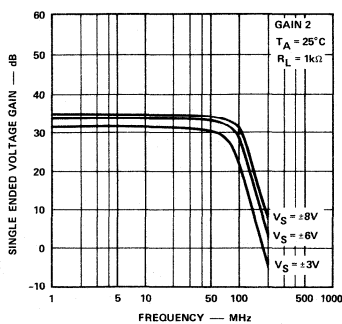
**GAIN VS FREQUENCY AS A FUNCTION OF TEMPERATURE**



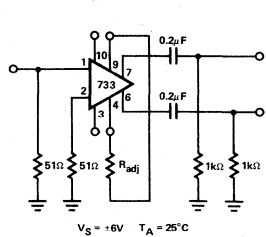
**VOLTAGE GAIN AS A FUNCTION OF SUPPLY VOLTAGE**



**GAIN VS FREQUENCY AS A FUNCTION OF SUPPLY VOLTAGE**

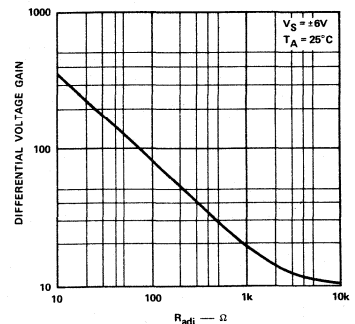


**VOLTAGE GAIN ADJUST CIRCUIT**



(Pin numbers apply to K Package)

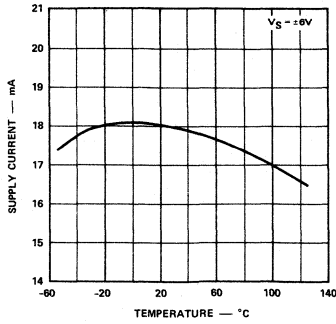
**VOLTAGE GAIN AS A FUNCTION OF R<sub>adj</sub> (FIGURE 3)**



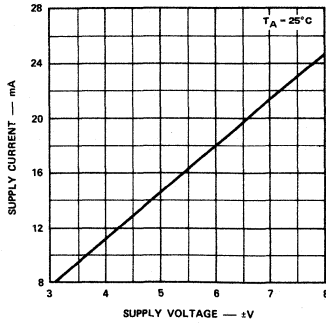
**FIGURE 3**

TYPICAL CHARACTERISTIC CURVES (Cont'd.)

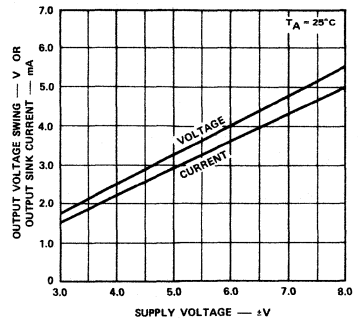
**SUPPLY CURRENT AS A FUNCTION OF TEMPERATURE**



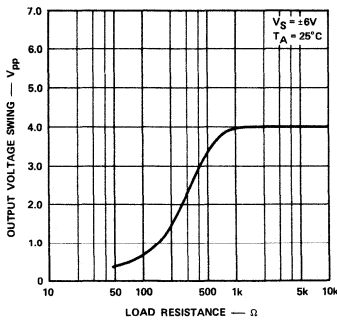
**SUPPLY CURRENT AS A FUNCTION OF SUPPLY VOLTAGE**



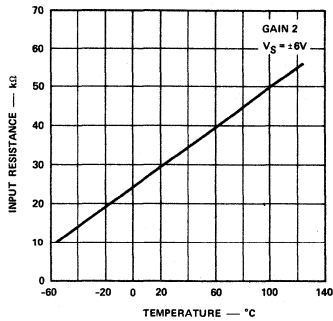
**OUTPUT VOLTAGE AND CURRENT SWING AS A FUNCTION OF SUPPLY VOLTAGE**



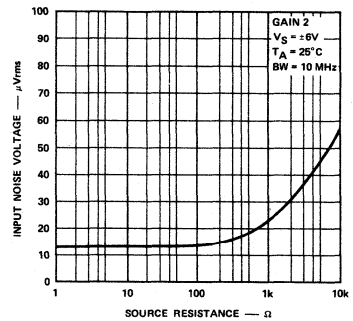
**OUTPUT VOLTAGE SWING AS A FUNCTION OF LOAD RESISTANCE**



**INPUT RESISTANCE AS A FUNCTION OF TEMPERATURE**



**INPUT NOISE VOLTAGE AS A FUNCTION OF SOURCE RESISTANCE**



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The  $\mu$ A740 is a special purpose high performance operational amplifier utilizing a FET input stage for high input impedance and low input current.

The device features internal compensation, standard pinout, wide differential and common mode input voltage range, high slew rate and high output drive capability.

### FEATURES

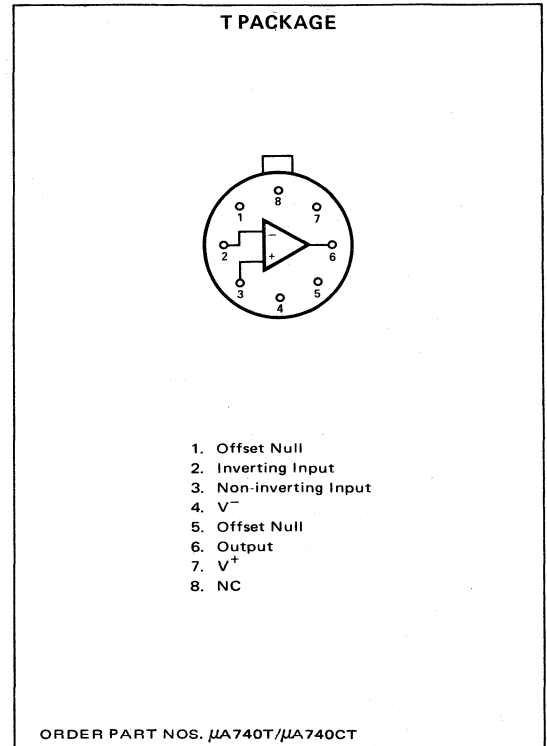
- 0.1 nA INPUT BIAS CURRENT
- INPUT AND OUTPUT PROTECTION
- OFFSET NULL CAPABILITY
- INTERNALLY COMPENSATED
- 6V/ $\mu$ sec SLEW RATE
- STANDARD PINOUT
- NO LATCH UP

### ABSOLUTE MAXIMUM RATING

Supply Voltage	$\pm 22$ V
Differential Input Voltage Range	$\pm 30$ V
Common Mode Input Voltage Range	$\pm V_S$
Power Dissipation (Note 1)	500mW
Operating Temperature Range	0°C to +70°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Solder, 60 sec)	300°C
Output short Circuit Duration (Note 2)	Indefinite

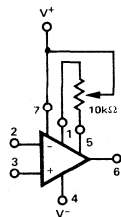
1. Rating applies for case temperatures to +25°C; derate linearly at 6.5mW/°C for ambient temperatures above 75°C.
2. Short circuit may be to ground or either supply. Rating applies to +125°C case temperature or +75°C ambient temperature.

### PIN CONFIGURATION (Top View)

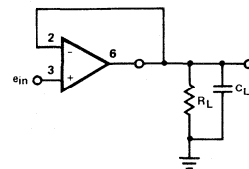


### TEST CIRCUITS

#### OFFSET NULL CIRCUIT



#### VOLTAGE FOLLOWER CIRCUIT





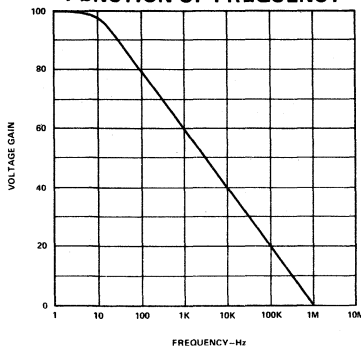
## SIGNETICS FET INPUT OPERATIONAL AMPLIFIER ■ $\mu$ A740

### ELECTRICAL CHARACTERISTICS ( $V_S = \pm 15$ V, $T_C = 25^\circ\text{C}$ unless otherwise specified)

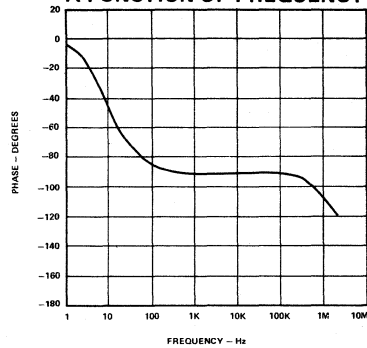
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	$R_S \leq 100$ k $\Omega$		30		mV
Input Offset Current			60		pA
Input Current (either input)			0.1	2.0	nA
Input Resistance	$R_L \geq 2$ k $\Omega$ , $V_{out} = \pm 10$ V		1,000,000		M $\Omega$
Large Signal Voltage Gain			1,000,000		
Output Resistance			75		$\Omega$
Output Short-Circuit Current			20		mA
Supply Current			4.2	3.0	mA
Power Consumption	$C_L \leq 100$ pF, $R_L = 2$ k $\Omega$ , $V_{in} = 100$ mV		126	240	mW
Slew Rate			6.0		V/ $\mu$ s
Unity Gain Bandwidth			1.0		MHz
Transient Response (Unity Gain)					
Risetime			300		ns
Overshoot			10		%
The following specifications apply for $0^\circ\text{C} \leq T_A \leq +70^\circ\text{C}$					
Input Voltage Range			$\pm 12$		V
Common Mode Rejection Ratio			80		db
Supply Voltage Rejection Ratio			70		$\mu$ V/V
Large Signal Voltage Gain	$R_L \geq 10$ k $\Omega$ $R_L \geq 2$ k $\Omega$		500,000		
Output Voltage Swing		$\pm 12$	$\pm 14$		V
		$\pm 10$	$\pm 13$		V
Input Offset Voltage			30		mV
Input Offset Current			60		pA
Input Current (either input)			1.1	10	nA

### TYPICAL CHARACTERISTIC CURVES

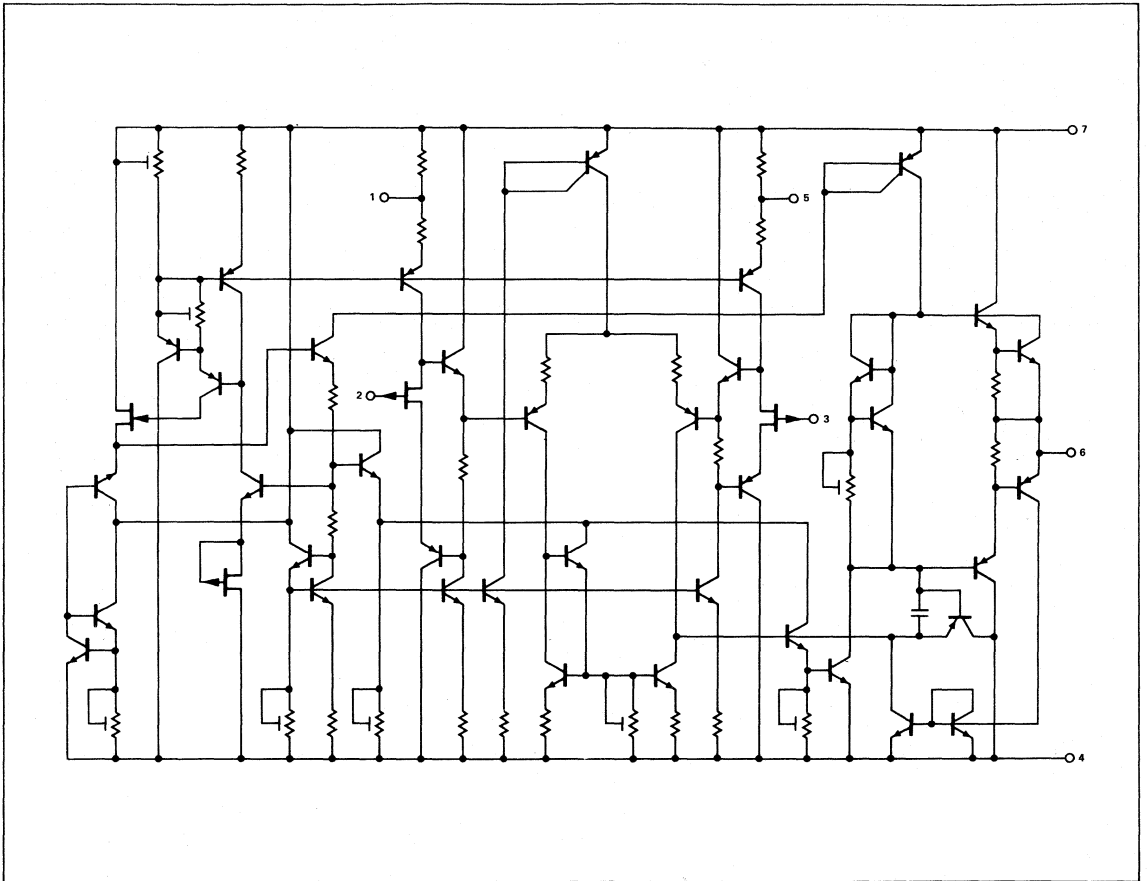
**OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF FREQUENCY**



**OPEN LOOP PHASE RESPONSE AS A FUNCTION OF FREQUENCY**



CIRCUIT SCHEMATIC



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The  $\mu$ A741 is a high performance operational amplifier with high open loop gain, internal compensation, high common mode range and exceptional temperature stability. The  $\mu$ A741 is short-circuit protected and allows for nulling of offset voltage.

### FEATURES

- INTERNAL FREQUENCY COMPENSATION
- SHORT CIRCUIT PROTECTION
- OFFSET VOLTAGE NULL CAPABILITY
- EXCELLENT TEMPERATURE STABILITY
- HIGH INPUT VOLTAGE RANGE
- NO LATCH-UP

### ABSOLUTE MAXIMUM RATINGS

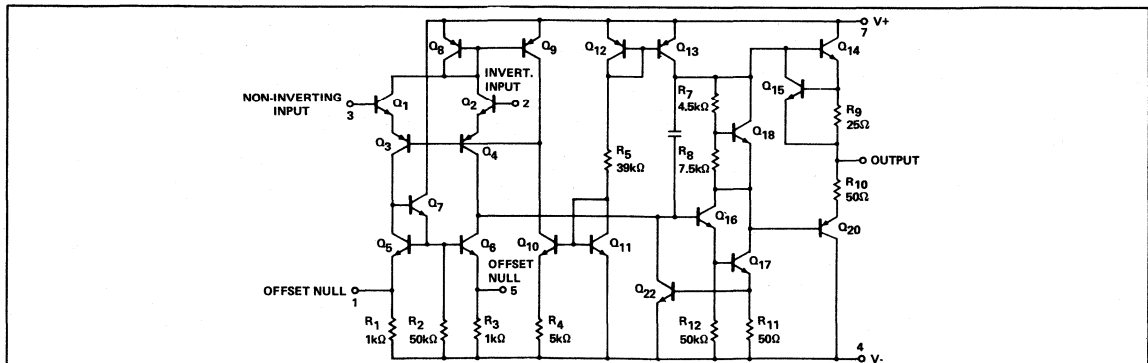
	$\mu$ A741C	$\mu$ A741
Supply Voltage	$\pm 18V$	$\pm 22V$
Internal Power		
Dissipation (Note 1)	500mW	500mW
Differential Input Voltage	$\pm 30V$	$\pm 30V$
Input Voltage (Note 2)	$\pm 15V$	$\pm 15V$
Voltage between Offset Null and $V^-$	$\pm 0.5V$	$\pm 0.5V$
Operating Temperature		
Range	$0^\circ C$ to $+70^\circ C$	$-55^\circ C$ to $+125^\circ C$
Storage Temperature		
Range	$-65^\circ C$ to $+150^\circ C$	$-65^\circ C$ to $+150^\circ C$

Lead Temperature		
(Solder, 60 sec)	$300^\circ C$	$300^\circ C$
Output Short Circuit	Indefinite	Indefinite
Duration (Note 3)		

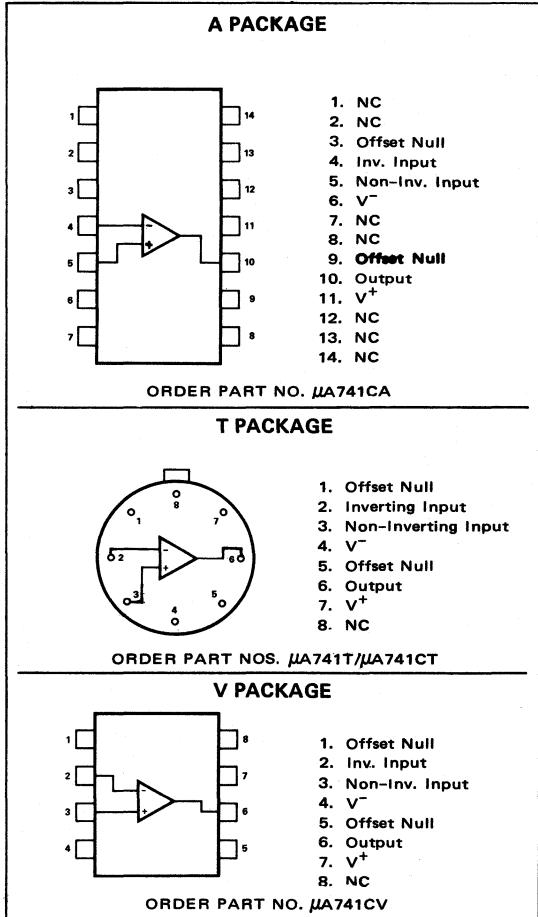
### Notes

1. Rating applies for case temperatures to  $125^\circ C$ ; derate linearly at  $6.5mW/^\circ C$  for ambient temperatures above  $+75^\circ C$ .
2. For supply voltages less than  $\pm 15V$ , the absolute maximum input voltage is equal to the supply voltage.
3. Short circuit may be to ground or either supply. Rating applies to  $+125^\circ C$  case temperature or  $+75^\circ C$  ambient temperature.

### EQUIVALENT CIRCUIT



### PIN CONFIGURATIONS (TOP VIEW)



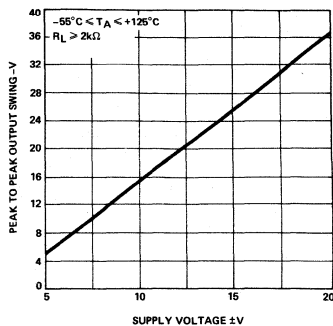
# SIGNETICS GENERAL PURPOSE OPERATIONAL AMPLIFIER ■ $\mu A741$

## ELECTRICAL CHARACTERISTICS ( $V_S = \pm 15V$ , $T_A = 25^\circ C$ unless otherwise specified)

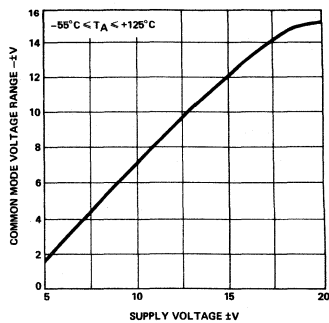
PARAMETER	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
$\mu A741C$					
Input Offset Voltage		2.0	6.0	mV	$R_S \leq 10k\Omega$
Input Offset Current		20	200	nA	
Input Bias Current		80	500	nA	
Input Resistance	0.3	2.0		M $\Omega$	
Input Capacitance		1.4		pF	
Offset Voltage Adjustment Range		$\pm 15$		mV	
Input Voltage Range	$\pm 12$	$\pm 13$		V	
Common Mode Rejection Ratio	70	90		dB	$R_S \leq 10k\Omega$
Supply Voltage Rejection Ratio		10	150	$\mu V/V$	$R_S \leq 10k\Omega$
Large-Signal Voltage Gain	20,000	200,000			$R_L \geq 2k\Omega$ , $V_{out} = \pm 10V$
Output Voltage Swing	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$		V	$R_L \geq 10k\Omega$ $R_L \geq 2k\Omega$
Output Resistance		75		$\Omega$	
Output Short-Circuit Current		25		mA	
Supply Current		1.4	2.8	mA	
Power Consumption		50	85	mW	
Transient Response (unity gain)					$V_{in} = 20mV$ , $R_L = 2k\Omega$ , $C_L \leq 100pF$
Risetime		0.3		$\mu s$	
Overshoot		5.0		%	
Slew Rate		0.5		V/ $\mu s$	$R_L \geq 2k\Omega$
The following specifications apply for $0^\circ C < T_A < +70^\circ C$					
Input Offset Voltage			7.5	mV	
Input Offset Current			300	nA	
Input Bias Current			800	nA	
Large-Signal Voltage Gain	15,000				$R_L \geq 2k\Omega$ , $V_{out} = \pm 10V$
Output Voltage Swing	$\pm 10$	$\pm 13$		V	$R_L \geq 2k\Omega$
$\mu A741$					
Input Offset Voltage		1.0	5.0	mV	$R_S \leq 10k\Omega$
Input Offset Current		10	200	nA	
Input Bias Current		80	500	nA	
Input Resistance	0.3	2.0		M $\Omega$	
Input Capacitance		1.4		pF	
Offset Voltage Adjustment Range		$\pm 15$		mV	
Large-Signal Voltage Gain	50,000	200,000			$R_L \geq 2k\Omega$ , $V_{out} = \pm 10V$
Output Resistance		75		$\Omega$	
Output Short Circuit Current		25		mA	
Supply Current		1.4	2.8	mA	
Power Consumption		50	85	mW	
Transient Response (unity gain)					$V_{in} = 20mV$ , $R_L = 2k\Omega$ , $C_L \leq 100pF$
Risetime		0.3		$\mu s$	
Overshoot		5.0		%	
Slew Rate		0.5		V/ $\mu s$	$R_L \geq 2k\Omega$
The following specifications apply for $-55^\circ C \leq T_A \leq +125^\circ C$					
Input Offset Voltage		1.0	6.0	mV	$R_S \leq 10k\Omega$
Input Offset Current		7.0	200	nA	$T_A = +125^\circ C$
		20	500	nA	$T_A = -55^\circ C$
Input Bias Current		0.03	0.5	$\mu A$	$T_A = +125^\circ C$
		0.3	1.5	$\mu A$	$T_A = -55^\circ C$
Input Voltage Range	$\pm 12$	$\pm 13$		V	
Common Mode Rejection Ratio	70	90		dB	$R_S \leq 10k\Omega$
Supply Voltage Rejection Ratio		10	150	$\mu V/V$	$R_S \leq 10k\Omega$
Large-Signal Voltage Gain	25,000				$R_L \geq 2k\Omega$ , $V_{out} = \pm 10V$
Output Voltage Swing	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$		V	$R_L \geq 10k\Omega$ $R_L \geq 2k\Omega$
Supply Current		1.5	2.5	mA	$T_A = +125^\circ C$
		2.0	3.3	mA	$T_A = -55^\circ C$
Power Consumption		45	75	mW	$T_A = +125^\circ C$
		45	100	mW	$T_A = -55^\circ C$

TYPICAL CHARACTERISTIC CURVES

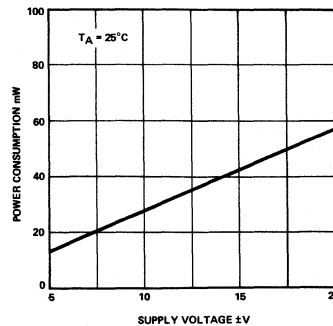
**OUTPUT VOLTAGE SWING AS A FUNCTION OF SUPPLY VOLTAGE**



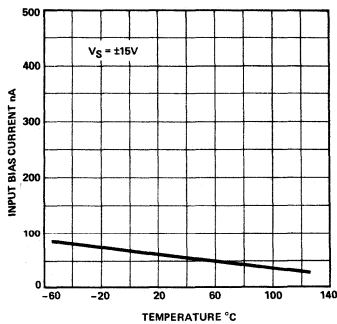
**INPUT COMMON MODE VOLTAGE RANGE AS A FUNCTION OF SUPPLY VOLTAGE**



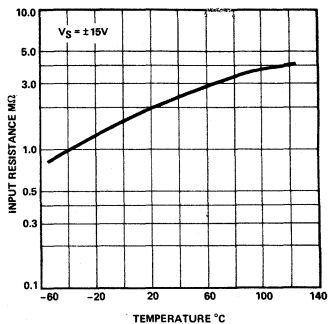
**POWER CONSUMPTION AS A FUNCTION OF SUPPLY VOLTAGE**



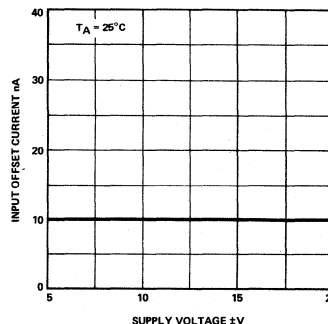
**INPUT BIAS CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



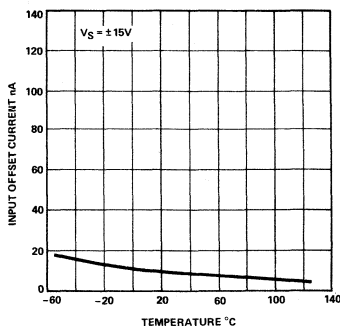
**INPUT RESISTANCE AS A FUNCTION OF AMBIENT TEMPERATURE**



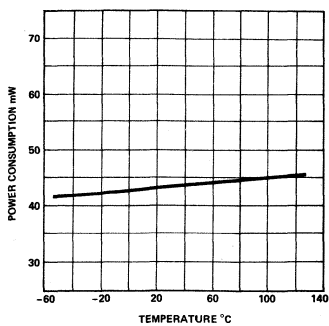
**INPUT OFFSET CURRENT AS A FUNCTION OF SUPPLY VOLTAGE**



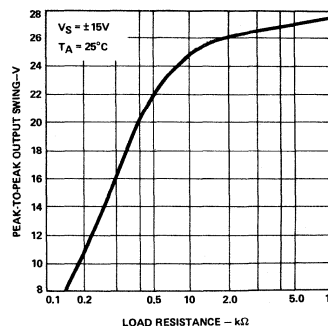
**INPUT OFFSET CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



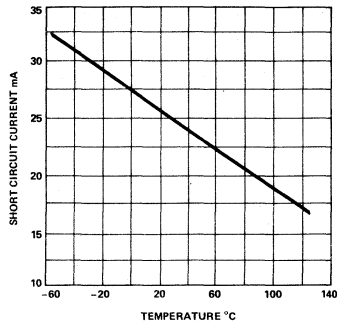
**POWER CONSUMPTION AS A FUNCTION OF AMBIENT TEMPERATURE**



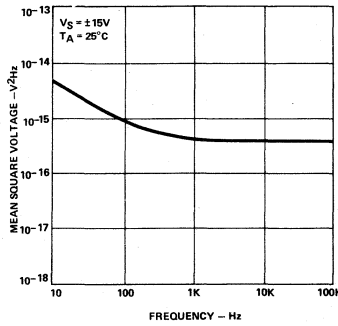
**OUTPUT VOLTAGE SWING AS A FUNCTION OF LOAD RESISTANCE**



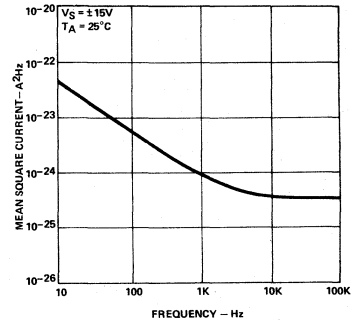
**OUTPUT SHORT-CIRCUIT CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



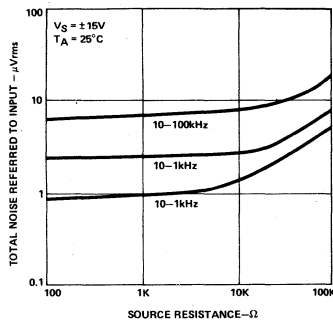
**INPUT NOISE VOLTAGE AS A FUNCTION OF FREQUENCY**



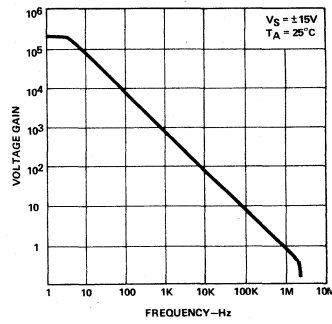
**INPUT NOISE CURRENT AS A FUNCTION OF FREQUENCY**



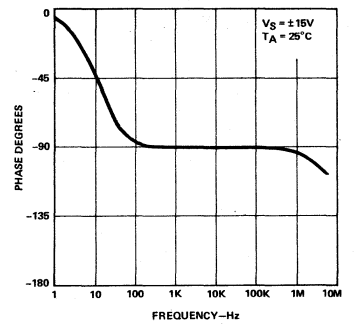
**BROADBAND NOISE FOR VARIOUS BANDWIDTHS**



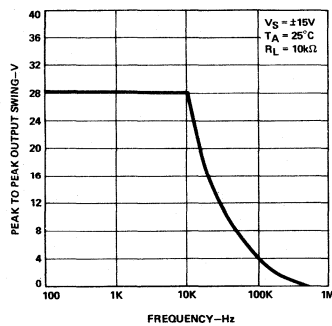
**OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF FREQUENCY**



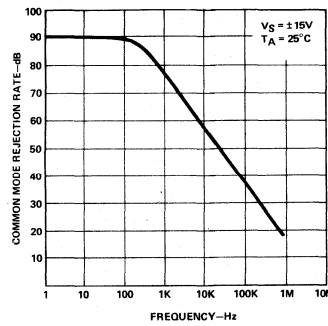
**OPEN LOOP PHASE RESPONSE AS A FUNCTION OF FREQUENCY**



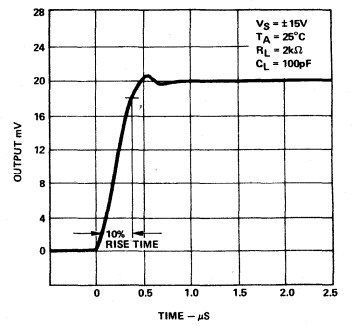
**OUTPUT VOLTAGE SWING AS A FUNCTION OF FREQUENCY**



**COMMON MODE REJECTION RATIO AS A FUNCTION OF FREQUENCY**



**TRANSIENT RESPONSE**



## LINEAR INTEGRATED CIRCUITS

### PIN CONFIGURATION (TOP VIEW)

### DESCRIPTION

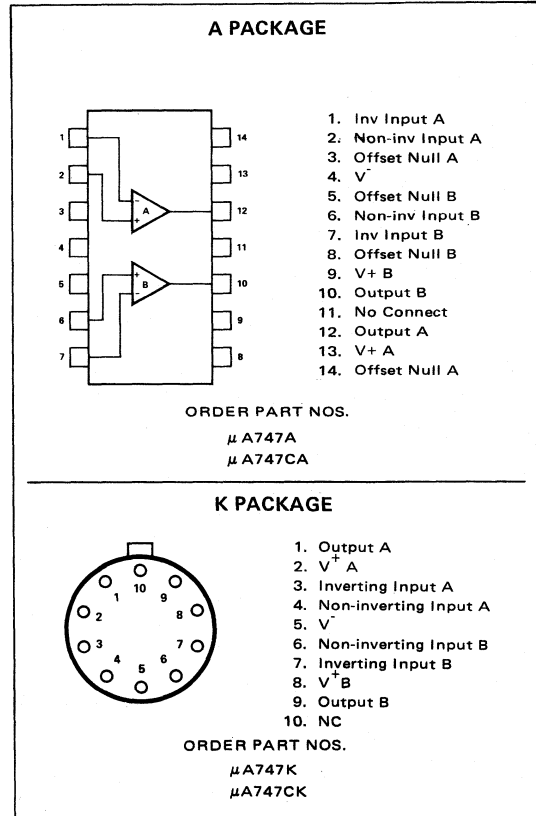
The  $\mu$ A747 is a pair of high performance monolithic operational amplifiers constructed on a single silicon chip. They are intended for a wide range of analog applications where board space or weight are important. High common mode voltage range and absence of "latch-up" make the  $\mu$ A747 ideal for use as a voltage follower. The high gain and wide range of operating voltage provides superior performance in integrator, summing amplifier, and general feedback applications. The  $\mu$ A747 is short-circuit protected and requires no external components for frequency compensation. The internal 6 db/octave roll-off insures stability in closed loop applications. For single amplifier performance, see  $\mu$ A741 data sheet.

### FEATURES

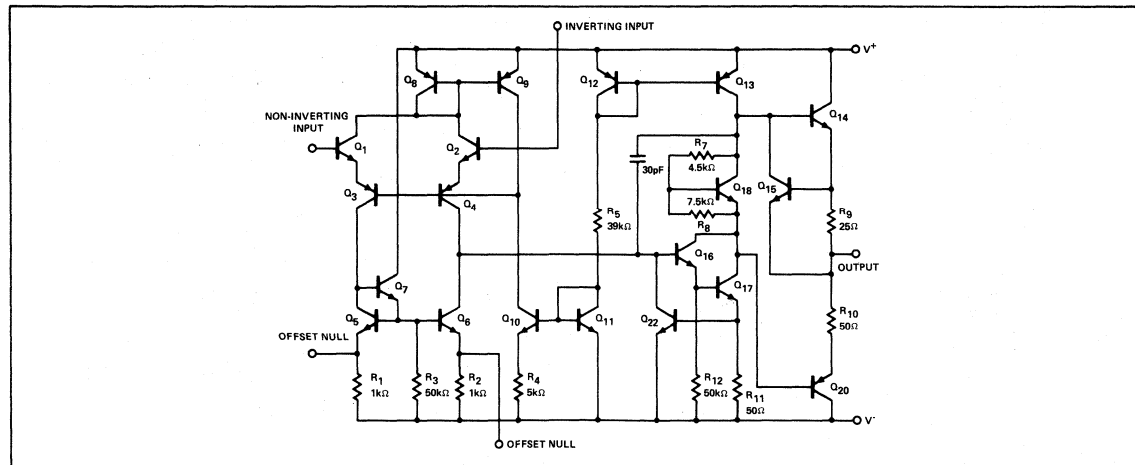
- NO FREQUENCY COMPENSATION REQUIRED
- SHORT-CIRCUIT PROTECTION
- OFFSET VOLTAGE NULL CAPABILITY
- LARGE COMMON-MODE AND DIFFERENTIAL VOLTAGE RANGES
- LOW POWER CONSUMPTION
- NO LATCH UP

### ABSOLUTE MAXIMUM RATINGS

Supply Voltage $\mu$ A747		+22V
$\mu$ A747C		+18V
Internal Power Dissipation (Note 1)	Metal Can	500 mW
	DIP	670 mW
Differential Input Voltage		+30V
Input Voltage (Note 2)		+15V
Voltage between Offset Null and $V^-$		+0.5V
Storage Temperature Range		-65°C to +155°C
Operating Temperature Range $\mu$ A747		-55°C to +125°C
	$\mu$ A747C	0°C to +70°C
Lead Temperature (Soldering 60 seconds)		300°C
Output Short Circuit Duration (Note 3)		Indefinite



### EQUIVALENT CIRCUIT (Each Side)



# SIGNETICS DUAL OPERATIONAL AMPLIFIER ■ $\mu A747$

## ELECTRICAL CHARACTERISTICS ( $V_S = \pm 15V$ , $T_A = 25^\circ C$ unless otherwise specified)

PARAMETERS	CONDITIONS	MIN.	TYP.	MAX.	UNITS
Input Offset Voltage	$R_S \leq 10k\Omega$		1.0		mV
$\mu A747$			5.0		mV
$\mu A747C$			6.0		mV
Input Offset Current			20	200	nA
Input Bias Current			80	500	nA
Input Resistance		0.3	2.0		M $\Omega$
Input Capacitance			1.4		pF
Offset Voltage Adjustment Range			$\pm 15$		mV
Large-Signal Voltage Gain	$R_L \geq 2k\Omega, V_{out} = \pm 10V$		200,000		
$\mu A747$		50,000			
$\mu A747C$		25,000			
Output Resistance			75		$\Omega$
Output Short-Circuit Current			25		mA
Supply Current			1.7	2.8	mA
Power Consumption			50	85	mW
Transient Response (unity gain)	$V_{in} = 20mV, R_L = 2k\Omega, C_L \leq 100pF$				
Risetime			0.3		$\mu S$
Overshoot			5.0		%
Slew Rate	$R_L \geq 2k\Omega$		0.5		V/ $\mu S$
Channel Separation			120		dB

### $\mu A747$

The following specifications apply for  $-55^\circ C \leq T_A \leq +125^\circ C$

Input Offset Voltage	$R_S \leq 10k\Omega$		1.0	6.0	mV
Input Offset Current	$T_A = +125^\circ C$		7.0	200	nA
	$T_A = -55^\circ C$		85	500	nA
Input Bias Current	$T_A = +125^\circ C$		0.03	0.5	$\mu A$
	$T_A = -55^\circ C$		0.3	1.5	$\mu A$
Input Voltage Range		$\pm 12$	$\pm 13$		V
Common Mode Rejection Ratio	$R_S \leq 10k\Omega$	70	90		dB
Supply Voltage Rejection Ratio	$R_S \leq 10k\Omega$		30	150	$\mu V/V$
Large-Signal Voltage Gain	$R_L \geq 2k\Omega, V_{out} = \pm 10V$	25,000			
Output Voltage Swing	$R_L \geq 10k\Omega$	$\pm 12$	$\pm 14$		V
	$R_L \geq 2k\Omega$	$\pm 10$	$\pm 13$		V
Supply Current	$T_A = +125^\circ C$		1.5	2.5	mA
	$T_A = -55^\circ C$		2.0	3.3	mA
Power Consumption	$T_A = +125^\circ C$		45	75	mW
	$T_A = -55^\circ C$		60	100	mW

### $\mu A747C$

The following specifications apply for  $0^\circ C \leq T_A \leq +70^\circ C$

Input Offset Voltage	$R_S \leq 10k\Omega$		1.0	7.5	mV
Input Offset Current			7.0	300	nA
Input Bias Current			0.03	0.8	$\mu A$
Input Voltage Range		$\pm 12$	$\pm 13$		V
Common Mode Rejection Ratio	$R_S \leq 10k\Omega$	70	90		dB
Supply Voltage Rejection Ratio	$R_S \leq 10k\Omega$		30	150	$\mu V/V$
Large-Signal Voltage Gain	$R_L \geq 2k\Omega, V_{out} = \pm 10V$	15,000			
Output Voltage Swing	$R_L \geq 10k\Omega$	$\pm 12$	$\pm 14$		V
	$R_L \geq 2k\Omega$	$\pm 10$	$\pm 13$		V
Supply Current			2.0	3.3	mA
Power Consumption			60	100	mW

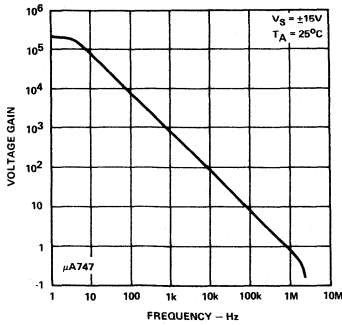
### NOTES:

- Rating applied to ambient temperatures up to  $70^\circ C$  ambient derate linearly at  $6.3mW/^\circ C$  for the Metal Can and  $8.3mW/^\circ C$  for the Ceramic DIP package.
- For supply voltages less than  $+15V$ , the absolute maximum input voltage is equal to the supply voltage.
- Short circuit may be to ground or either supply. Military rating applies to  $+125^\circ C$  case temperature or  $+60^\circ C$  ambient temperature for each side.

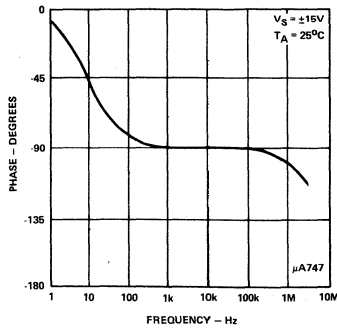


TYPICAL CHARACTERISTIC CURVES

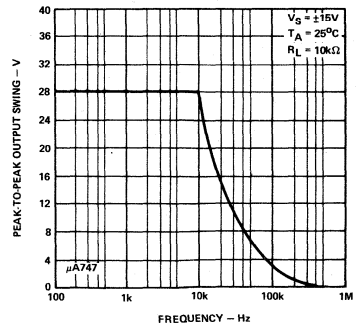
OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF FREQUENCY



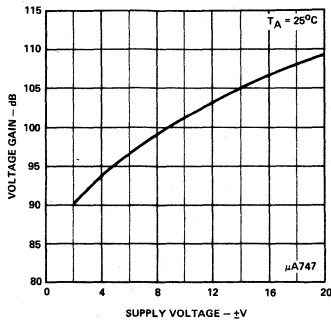
OPEN LOOP PHASE RESPONSE AS A FUNCTION OF FREQUENCY



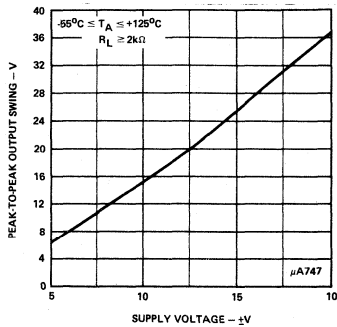
OUTPUT VOLTAGE SWING AS A FUNCTION OF FREQUENCY



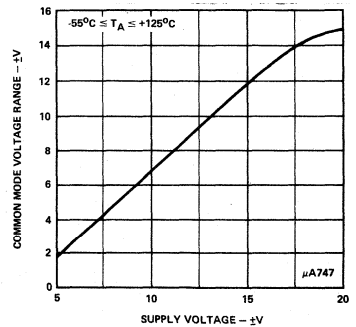
OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF SUPPLY VOLTAGE



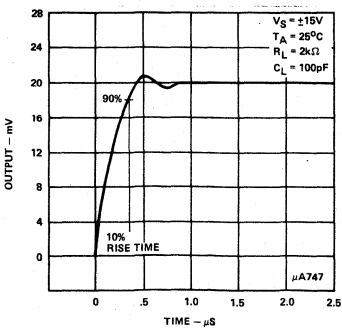
OUTPUT VOLTAGE SWING AS A FUNCTION OF SUPPLY VOLTAGE



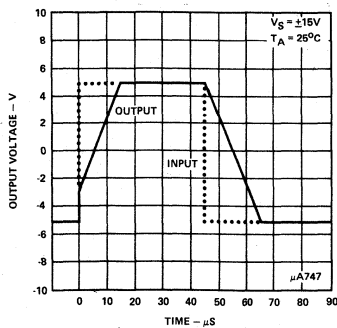
INPUT COMMON MODE VOLTAGE RANGE AS A FUNCTION OF SUPPLY VOLTAGE



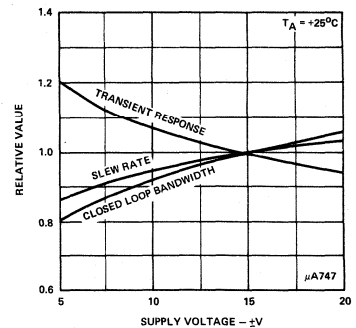
TRANSIENT RESPONSE



VOLTAGE FOLLOWER LARGE-SIGNAL PULSE RESPONSE

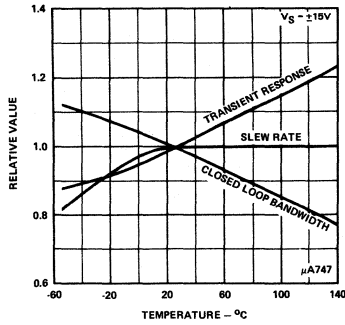


FREQUENCY CHARACTERISTICS AS A FUNCTION OF SUPPLY VOLTAGE

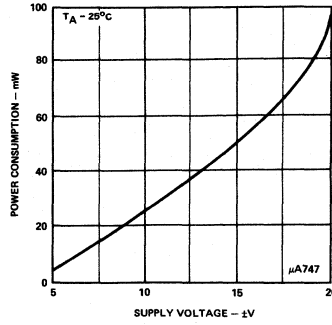


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

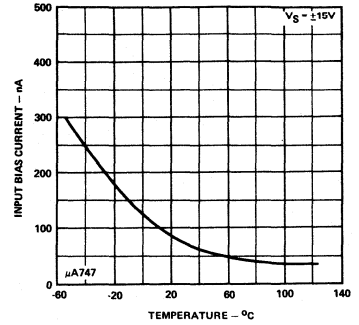
FREQUENCY CHARACTERISTICS AS A FUNCTION OF AMBIENT TEMPERATURE



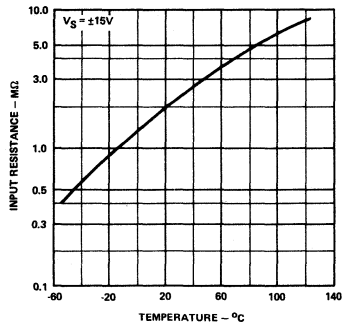
POWER CONSUMPTION AS A FUNCTION OF SUPPLY VOLTAGE



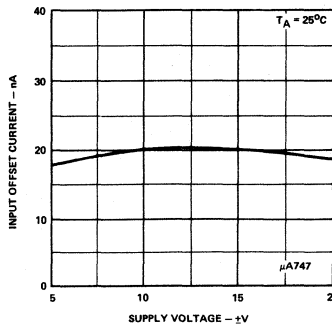
INPUT BIAS CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE



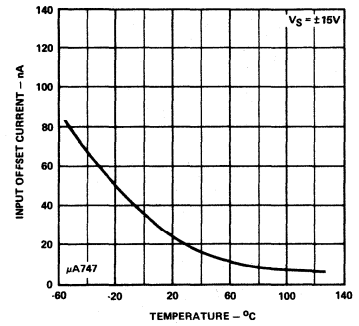
INPUT RESISTANCE AS A FUNCTION OF AMBIENT TEMPERATURE



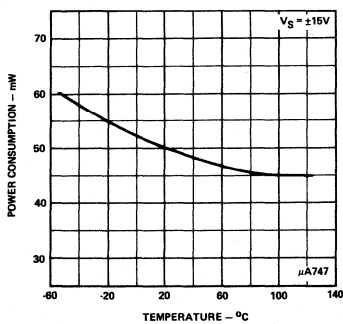
INPUT OFFSET CURRENT AS A FUNCTION OF SUPPLY VOLTAGE



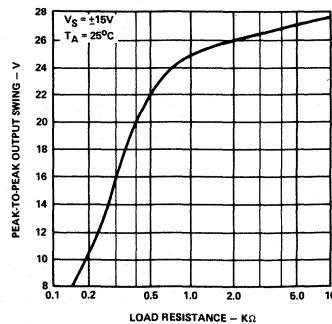
INPUT OFFSET CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE



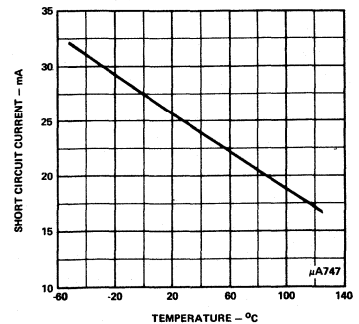
POWER CONSUMPTION AS A FUNCTION OF AMBIENT TEMPERATURE



OUTPUT VOLTAGE SWING AS A FUNCTION OF LOAD RESISTANCE

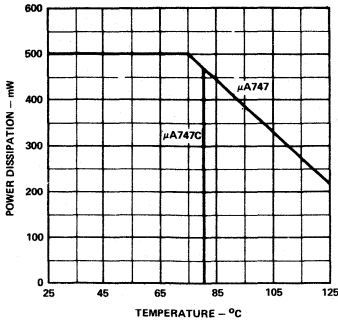


OUTPUT SHORT-CIRCUIT CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE

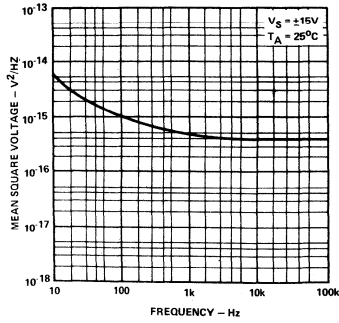


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

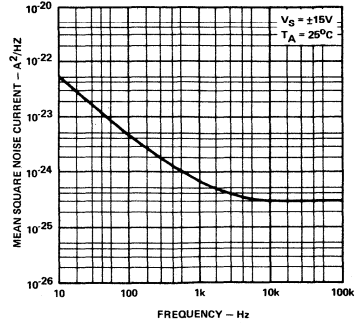
**ABSOLUTE MAXIMUM POWER DISSIPATION AS A FUNCTION OF AMBIENT TEMPERATURE**



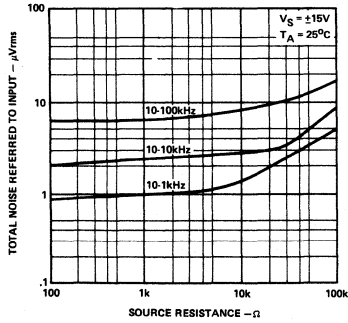
**INPUT NOISE VOLTAGE AS A FUNCTION OF FREQUENCY**



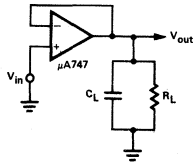
**INPUT NOISE CURRENT AS A FUNCTION OF FREQUENCY**



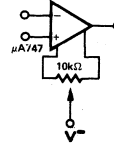
**BROADBAND NOISE FOR VARIOUS BANDWIDTHS**



**TRANSIENT RESPONSE TEST CIRCUIT**



**VOLTAGE OFFSET NULL CIRCUIT**



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The  $\mu$ A748 is a High Performance Operational Amplifier featuring high gain, short circuit immunity, offset voltage null capability, simplified compensation and excellent temperature stability.

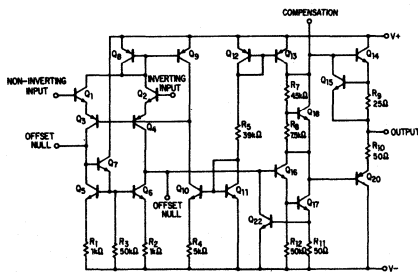
### FEATURES

- SHORT CIRCUIT PROTECTION
- OFFSET VOLTAGE NULL CAPABILITY
- LARGE COMMON-MODE AND DIFFERENTIAL VOLTAGE RANGES
- LOW POWER CONSUMPTION
- NO LATCH UP

### ABSOLUTE MAXIMUM RATINGS

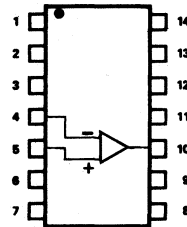
Supply Voltage	
$\mu$ A748	$\pm 22V$
$\mu$ A748C	$\pm 18V$
Internal Power Dissipation (Note 1)	500mW
Differential Input Voltage	$\pm 30V$
Input Voltage (Note 2)	$\pm 15V$
Storage Temperature Range	$-65^{\circ}C$ to $+150^{\circ}C$
Operating Temperature Range	
$\mu$ A748	$-55^{\circ}C$ to $+125^{\circ}C$
$\mu$ A748C	$0^{\circ}C$ to $+70^{\circ}C$
Lead Temperature	$300^{\circ}C$
Output Short Circuit Duration (Note 3)	Indefinite

### EQUIVALENT CIRCUIT



### PIN CONFIGURATIONS (Top View)

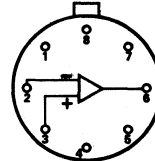
#### A PACKAGE



1. NC
2. NC
3. Freq. Comp. A/Offset Null
4. Inverting Input
5. Noninverting Input
6.  $V^-$
7. NC
8. NC
9. Offset Null
10. Output
11.  $V^+$
12. Freq. Comp. B
13. NC
14. NC

ORDER PART NOS.  
 $\mu$ A748A/ $\mu$ A748CA

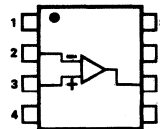
#### T PACKAGE



1. Freq. Comp A/Offset Null
2. Inverting Input
3. Noninverting Input
4.  $V^-$
5. Offset Null
6. Output
7.  $V^+$
8. Freq. Comp. B

ORDER PART NOS.  
 $\mu$ A748T/ $\mu$ A748CT

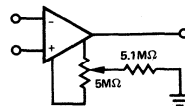
#### V PACKAGE



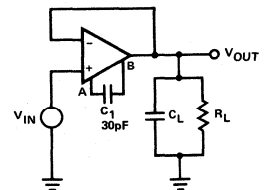
1. Freq. Comp. A/ Offset Null.
2. Inverting Input
3. Noninverting Input
4.  $V^-$
5. Offset Null
6. Output
7.  $V^+$
8. Freq. Comp. B

ORDER PART NO.  
 $\mu$ A748CV

### VOLTAGE OFFSET NULL CIRCUIT



### TRANSIENT RESPONSE TEST CIRCUIT



### NOTES:

1. Rating applies for case temperatures to  $+70^{\circ}C$ .
2. For supply voltages less than  $\pm 15V$ , the absolute maximum input voltage is equal to the supply voltage.
3. Short circuit may be to ground or either supply. Rating applies to  $+70^{\circ}C$  ambient temperature.

**SIGNETICS GENERAL PURPOSE OPERATIONAL AMPLIFIER ■  $\mu$ A748**

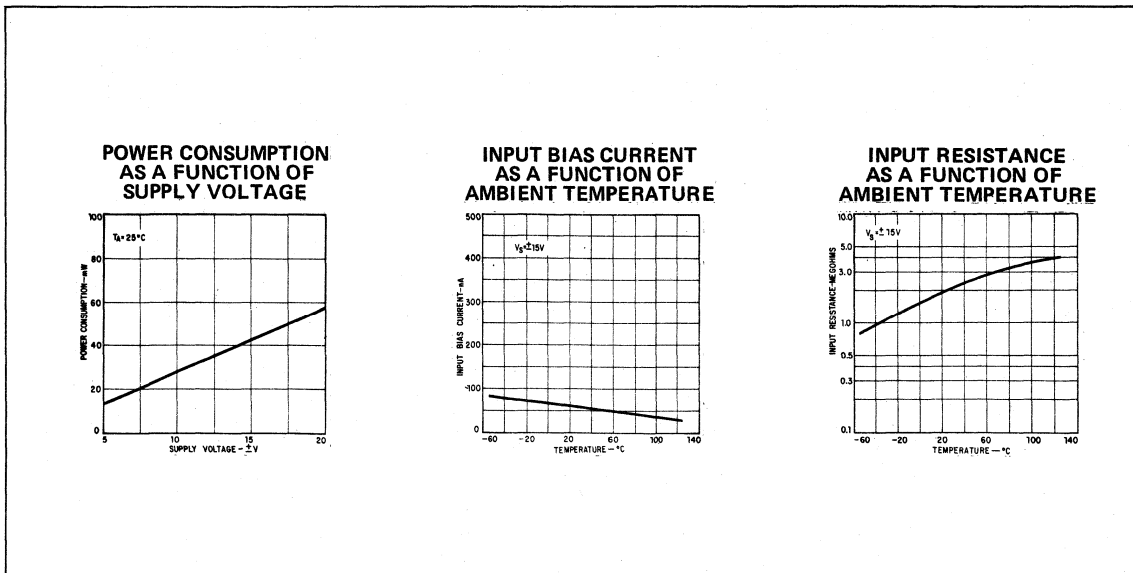
**ELECTRICAL CHARACTERISTICS** ( $V_S = \pm 15V$ ,  $T_A = 25^\circ C$  unless otherwise specified)

PARAMETER	CONDITIONS	$\mu$ A748C			$\mu$ A748			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Input Offset Voltage	$R_S \leq 10\text{ k}\Omega$		2.0	6.0		1.0	5.0	mV
Input Offset Current			20	200		20	200	nA
Input Bias Current			80	500		80	500	nA
Input Resistance		0.3	2.0		0.3	2.0		M $\Omega$
Input Capacitance			1.4			1.4		pF
Offset Voltage Adjustment Range			$\pm 15$			$\pm 15$		mV
Input Voltage Range		$\pm 12$	$\pm 13$		$\pm 12$	$\pm 13$		V
Large-Signal Voltage Gain	$R_L \geq 2\text{ k}\Omega$ , $V_{out} \neq \pm 10V$	50K	200K		50K	200K		
Output Resistance			75			75		$\Omega$
Output Short-Circuit Current			25			25		mA
Supply Voltage Rejection Ratio	$R_S \leq 10\text{ k}\Omega$		30	150		30	150	$\mu$ V/V
Common Mode Rejection Ratio	$R_S \leq 10\text{ k}\Omega$	70	90		70	90		dB
Supply Current			1.7	2.8		1.7	2.8	mA
Power Consumption			50	85		50	85	mW
Transient Response (unity gain)	$V_{in} = 20\text{mV}$ , $R_L = 2\text{ k}\Omega$ , $C_L \leq 100\text{ pF}$							
Risetime	$C_1 = 30\text{ pF}$		0.3			0.3		$\mu$ s
Overshoot			5.0			5.0		%
Slew Rate	$R_L \geq 2\text{ k}\Omega$ $C_1 = 30\text{ pF}$		0.5			0.5		V/ $\mu$ s

**The Following Specifications Apply Over the Operating Temperature Ranges**

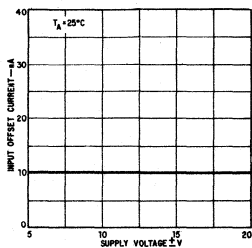
Input Offset Voltage	$R_S \leq 10\text{ k}\Omega$			7.5			6.0	mV
Input Offset Current	$T_A$ max		9.0	300		7.0	200	nA
	$T_A$ min		35	300		85	500	nA
Input Bias Current	$T_A$ max		0.04	0.8		0.03	0.5	$\mu$ A
	$T_A$ min		0.13	0.8		0.3	1.5	$\mu$ A
Input Voltage Range		$\pm 12$	$\pm 13$		$\pm 12$	$\pm 13$		V
Common Mode Rejection Ratio	$R_S \leq 10\text{ k}\Omega$	70	90		70	90		dB
Supply Voltage Rejection Ratio	$R_S \leq 10\text{ k}\Omega$		30	150		30	150	$\mu$ V/V
Large-Signal Voltage Gain	$R_L \geq 2\text{ k}\Omega$ , $V_{out} = \pm 10V$		25			25		V/mV
Output Voltage Swing	$R_L \geq 10\text{ k}\Omega$	$\pm 12$	$\pm 14$		$\pm 12$	$\pm 14$		V
	$R_L \geq 2\text{ k}\Omega$	$\pm 10$	$\pm 13$		$\pm 10$	$\pm 13$		V
Supply Current	$T_A$ max		1.6	3.3		1.5	2.5	mA
	$T_A$ min		1.8	3.3		2.0	3.3	mA
Power Consumption	$T_A$ max		48	100		45	75	mW
	$T_A$ min		54	100		60	100	mW

**TYPICAL CHARACTERISTIC CURVES**

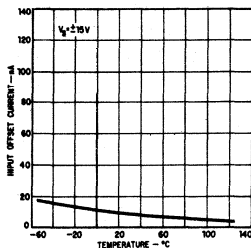


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

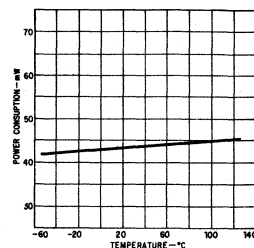
**INPUT OFFSET CURRENT AS A FUNCTION OF SUPPLY VOLTAGE**



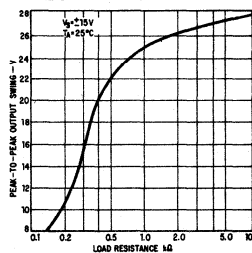
**INPUT OFFSET CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



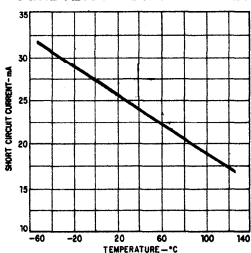
**POWER CONSUMPTION AS A FUNCTION OF AMBIENT TEMPERATURE**



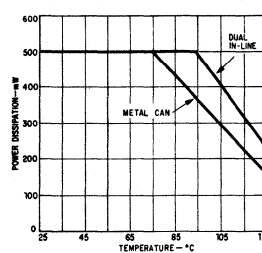
**OUTPUT VOLTAGE SWING AS A FUNCTION OF LOAD RESISTANCE**



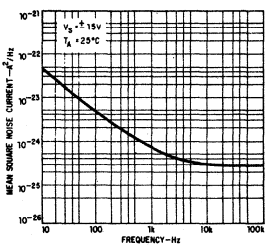
**OUTPUT SHORT-CIRCUIT CURRENT AS A FUNCTION OF AMBIENT TEMPERATURE**



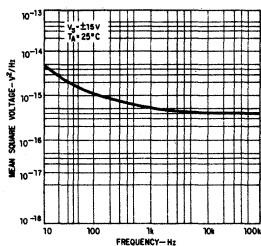
**ABSOLUTE MAXIMUM POWER DISSIPATION AS A FUNCTION OF AMBIENT TEMPERATURE**



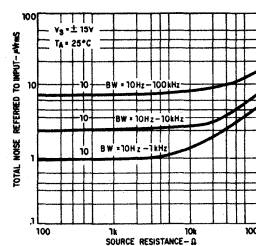
**INPUT NOISE CURRENT AS A FUNCTION OF FREQUENCY**



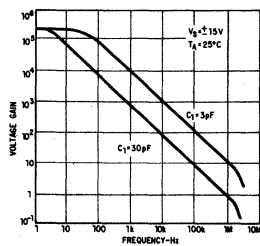
**INPUT NOISE VOLTAGE AS A FUNCTION OF FREQUENCY**



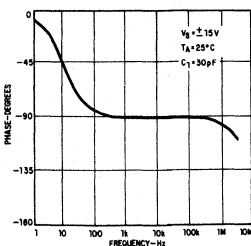
**BROADBAND NOISE AS A FUNCTION OF SOURCE RESISTANCE**



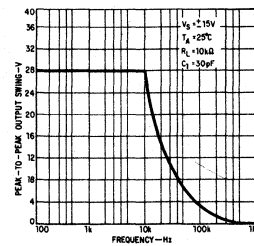
**OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF FREQUENCY**



**OPEN LOOP PHASE RESPONSE AS A FUNCTION OF FREQUENCY**

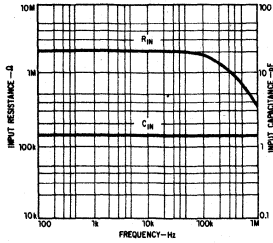


**OUTPUT VOLTAGE SWING AS A FUNCTION OF FREQUENCY**

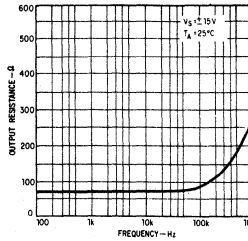


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

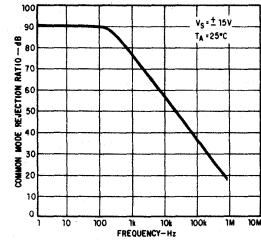
INPUT RESISTANCE AND INPUT CAPACITANCE AS A FUNCTION OF FREQUENCY



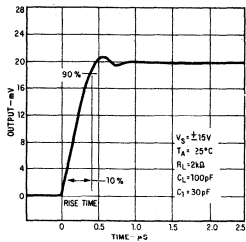
OUTPUT RESISTANCE AS A FUNCTION OF FREQUENCY



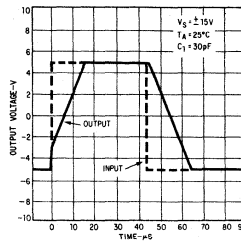
COMMON MODE REJECTION RATIO AS A FUNCTION OF FREQUENCY



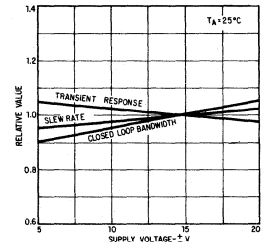
TRANSIENT RESPONSE



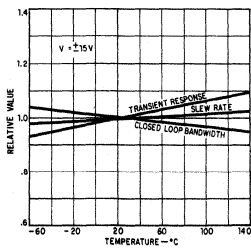
VOLTAGE FOLLOWER LARGE-SIGNAL PULSE RESPONSE



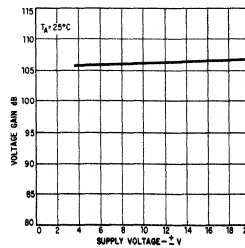
FREQUENCY CHARACTERISTICS AS A FUNCTION OF SUPPLY VOLTAGE



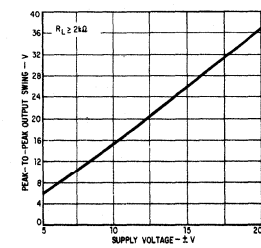
FREQUENCY CHARACTERISTICS AS A FUNCTION OF AMBIENT TEMPERATURE



OPEN LOOP VOLTAGE GAIN AS A FUNCTION OF SUPPLY VOLTAGE



OUTPUT VOLTAGE SWING AS A FUNCTION OF SUPPLY VOLTAGE



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The PA239 is a dual low noise preamplifier featuring two identically-matched 68dB gain amplifiers fed from an internal zener regulated power supply. Operation requires only a single power supply and a minimum number of external frequency shaping components.

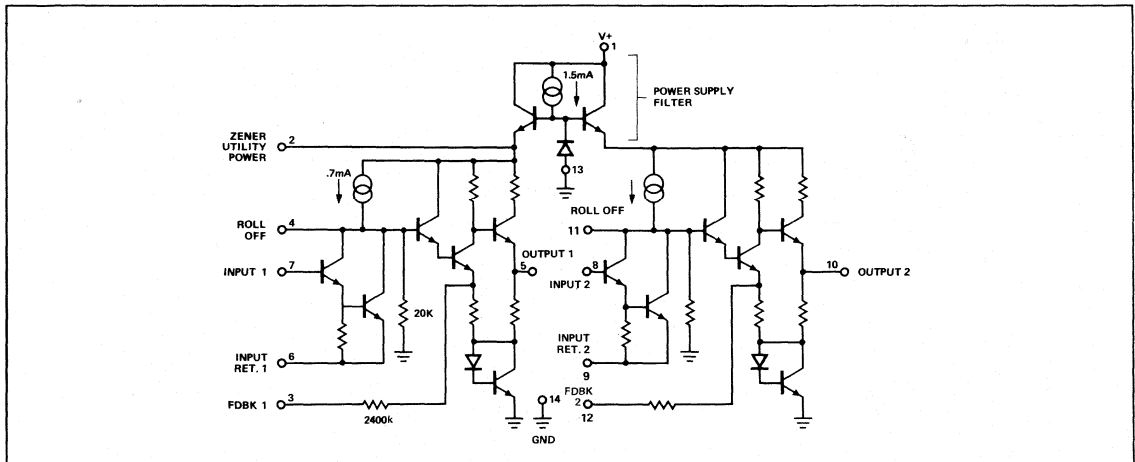
### FEATURES

- MATCHED OPEN LOOP VOLTAGE GAIN
- LOW AUDIO NOISE
- SINGLE POWER SUPPLY
- WIDE POWER SUPPLY RANGE
- BUILT-IN POWER SUPPLY FILTER
- HIGH INPUT IMPEDANCE
- EMITTER FOLLOWER OUTPUT
- LOW DISTORTION
- SELF BIASING
- MINIMUM NUMBER OF EXTERNAL COMPONENTS
- OUTPUT CIRCUIT IS SHORT CIRCUIT PROTECTED
- HIGH CHANNEL SEPARATION
- VARIETY OF FEEDBACK OPTIONS
- NO CIRCUIT DAMAGE IF PLUGGED IN BACKWARDS
- 7.5V REGULATOR BIAS SOURCE

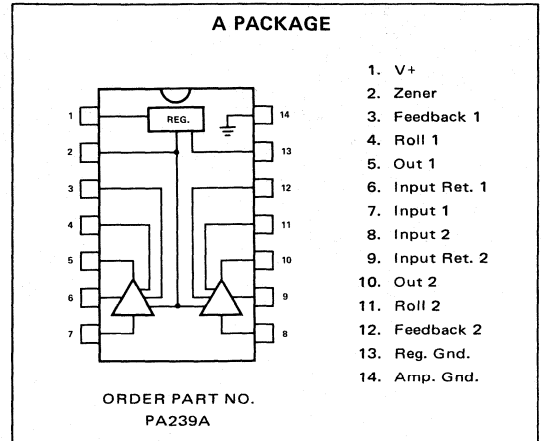
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	16V
Temperature	
Storage	-55°C to +150°C
Operating	-30°C to +85°C

### SCHEMATIC DIAGRAM



### PIN CONFIGURATION (Top View)



### APPLICATIONS

- STEREO TAPE PLAYERS/RECORDERS
- DICTATING EQUIPMENT
- MOVIE PROJECTORS
- PHONOGRAPHS
- TV REMOTE CONTROL RECEIVER
- MICROPHONE AMPLIFIERS
- STEREO RADIO RECEIVER SYSTEMS
- VIDEO PREAMPLIFICATION
- NARROW BAND AMPLIFICATION
- DRIVER-PREAMP FOR LOSSY NETWORKS
- SUPER GAIN CASCADED AMPLIFIERS



ELECTRICAL CHARACTERISTICS (25°C) ( $V_{CC} = 12V$ )

PARAMETERS	MIN	TYP	MAX	UNITS
Supply Current ( $V_{CC} = 12V$ )		16	22	mA
Voltage Gain	65	68	71	dB
Gain Balance		0.3	2	dB
Channel Separation ( $f = 1$ kHz), Figure 1	45	90		dB
Input Resistance	100K	250K		$\Omega$
Signal Output		1.5		Vrms
Output Resistance		100		$\Omega$
Power Supply Rejection ( $f = 1$ kHz), Figure 2	45	55		dB
Total Harmonic Distortion Without Feedback (0.5V rms into $3k\Omega$ Load, 1 kHz)		0.5	0.9	%
Input dc Bias Current		0.8	3	$\mu A$
Gain to Feedback Terminal 3, 12		45		dB
Impedance at Feedback Terminal		2400		$\Omega$
Amplifier Noise Figure (100Hz to 10 kHz, $5k\Omega$ Rs)		1.8		dB
Equivalent Input Noise (100Hz to 10 kHz, $680\Omega$ Rs)		0.7	1.2	$\mu V$

TEST CIRCUITS

CHANNEL SEPARATION

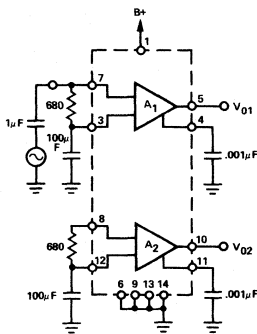


Figure 1

POWER SUPPLY REJECTION

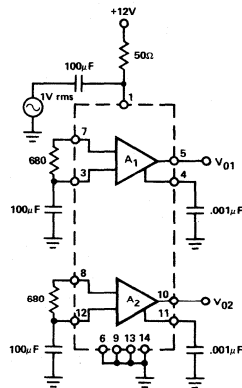


Figure 2

NOISE

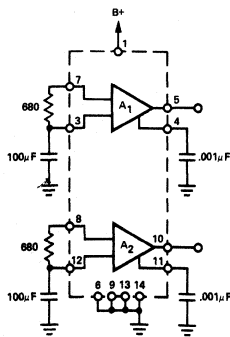


Figure 3

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

A unique method of FM detection by a new technique of linear gating is featured in the ULN2111 monolithic integrated circuit. This linear device comprises a three-stage limiter and a balanced product detector. Applications for the ULN2111 device include TV sound channels, FM receivers, automatic frequency control systems, and communication receivers.

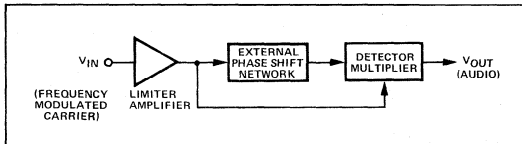
Other applications for the ULN2111 device are in the more sophisticated circuitry in telemetry receivers, automatic control systems, and servo amplifiers.

An outstanding feature of the ULN2111 is that only one, simple, low-cost, single winding coil is required for tuning. Consequently, only one screwdriver adjustment is required to tune a detector employing the ULN2111. The frequency range of the ULN2111 extends from 5 kHz to 50 MHz. Outputs of 0.6V with a total distortion of less than 1% and a limiting threshold voltage of  $400\mu\text{V}_{\text{rms}}$  are typical.

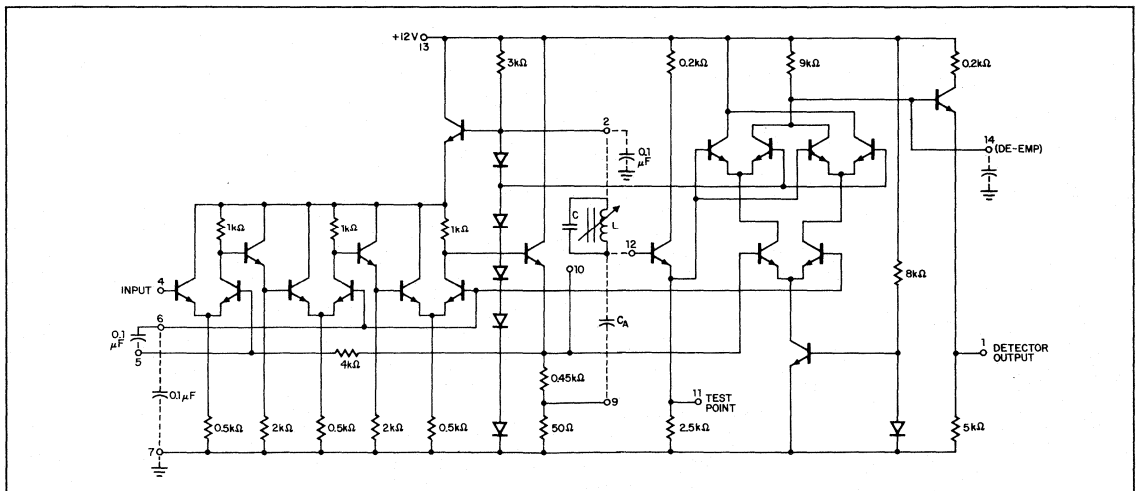
### FEATURES

- HIGH SENSITIVITY – INPUT LIMITING VOLTAGE AT 4.5MHz =  $400\mu\text{V}$
- HIGH IF VOLTAGE GAIN – 60dB
- SIMPLIFIED TUNING – ONE RLC PHASE SHIFT NETWORK
- HIGH STABILITY
- LOW DISTORTION – 1.0%
- WIDE FREQUENCY CAPABILITY – 5kHz to 50MHz

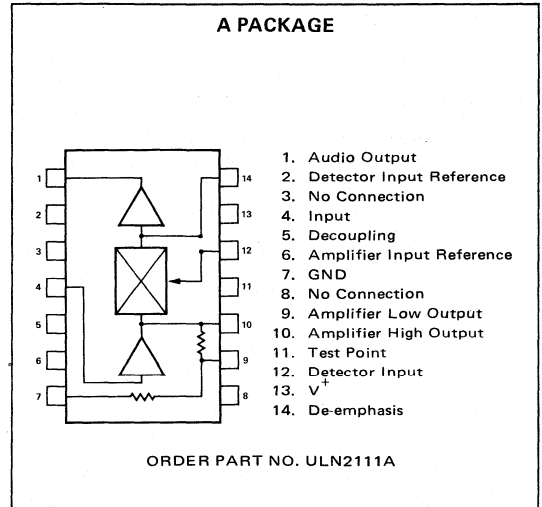
### BLOCK DIAGRAM



### BASIC CIRCUIT SCHEMATIC



### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS

Input Voltage (Pin 4)	+3.5V
Output Voltage	+15V
Supply Voltage (V+)	+15V
Junction Temperature	+150°C
Storage Temperature	-65°C to +150°C
Operating Temperature	0°C to +85°C
Thermal Resistance	0.15°C/mW
$\theta_{J-A}$ , Junction to Ambient	
Power Dissipation	300mW

# SIGNETICS FM DETECTOR AND LIMITER ■ ULN2111

## ELECTRICAL CHARACTERISTICS

Standard Conditions:  $V_{CC} = +12V \pm 10\%$ ,  $T_A = 25^\circ C$

CHARACTERISTICS	SYMBOL	LIMITS				TEST CONDITIONS	TEST FIGURE	NOTES
		MIN	TYP	MAX	UNITS			
Supply Current	$I_{CC}$	12.0	17	22	mA		Pin 13	
Amplifier Input Reference	$V_{bias}$		1.45		V	Internally derived	6	
Detector Input Reference	$V_{bias}$		3.65		V	Internally derived	2	
Amplifier High Output Level	$V_{oh}$		1.45		V		10	
Amplifier Low Output Level	$V_{ol}$		0.145		V		9	
Detector Output Level	$V_o$	4.3	5.0	5.7	V		1	
Amplifier Input Resistance	$R_{in}$		5.0		K $\Omega$		4	
Amplifier Input Capacitance	$C_{in}$		11		pF		4	
Detector Injection Input Resistance	$R_{in}$		70		K $\Omega$		12	
Detector Injection Input Capacitance	$C_{in}$		2.7		pF		12	
Amplifier High Output Resistance	$R_{out}$		60		$\Omega$		10	
Detector Output Resistance	$R_{out}$		200		$\Omega$		1	
De-Emphasis Resistance	$R_{de}$		9		K $\Omega$		14	
FM Detection for Television Applications:						Detector injection voltage = $60mV_{rms}$ , $f_o = 4.5$ MHz, F deviation = 25 kHz, Peak separation = 150 kHz, FM modulating frequency = 400 Hz, Amplifier source resistance = $50\Omega$ .		
Amplifier Voltage Gain	$V_g$	55	58		dB	$V_{in} \leq 0.3mV_{rms}$ $V_{cc} = 12V \pm 5\%$	10	1
Amplifier Output Voltage	$V_{oa}$		1.45		$V_{pp}$	$V_{in} = 10mV_{rms}$	10	1
Input Limiting Threshold	$V_{th}$		400	800	$\mu V_{rms}$		4	2
Recovered Audio Output	$A_{vo}$	0.5	0.6		$V_{rms}$		1	2
Output Distortion	$T_{hd}$		1.5		%	100% FM Modulation	1	2
AM Suppression	AMR	40	46		dB	$V_{in} = 10mV_{rms}$	1	3
FM Detection for 10.7 MHz Applications:						Detector injection voltage = $60mV_{rms}$ , $f_o = 10.7$ MHz, F deviation = 75 kHz, Peak separation = 550 kHz, FM modulating frequency = 400 Hz, Amplifier source resistance = $50\Omega$ .		
Amplifier Voltage Gain	$V_g$		53		dB	$V_{in} \leq 0.3mV_{rms}$ $V_{cc} = 12V \pm 5\%$ .	10	1
Amplifier Output Voltage	$V_{oa}$		1.45		$V_{pp}$	$V_{in} = 10mV_{rms}$	10	1
Input Limiting Threshold	$V_{th}$		500		$\mu V_{rms}$		4	2
Recovered Audio Output	$A_{vo}$		0.45		$V_{rms}$		1	2
Output Distortion	$T_{hd}$		1.0		%	100% FM modulation	1	2
AM Suppression	AMR		40		dB	$V_{in} = 10mV_{rms}$	1	3

**NOTES**

- The limiting threshold voltage is the FM input voltage  $V_i$ , expressed in rms volts, for a recovered  $V_{out}$  which is 3dB less than the recovered  $V_{out}$  at a  $V_i$  of  $200mV_{rms}$ .
- The Amplitude Modulation Rejection in decibels, often abbreviated AMR, is given by the following formula:

$$AMR = 20 \log \frac{V_{out} \text{ for } 100\% \text{ FM modulated } V_i}{V_{out} \text{ for a } 30\% \text{ AM } V_i}$$

# SIGNETICS FM DETECTOR AND LIMITER ■ ULN2111

## USEAGE INFORMATION

### 1. FM DETECTION.

- a. Tuning. Apply FM modulated signal through DC decoupling network to pin 4,  $V_{in} = 5mV_{rms}$ . Tune for maximum recovered audio at pin 1 or maximum RF voltage at pin 11.
- b. General
  - (1) A DC path less than  $100\Omega$  shall be provided between pins 2 and 12. No other biasing provisions are required.
  - (2) A DC path less than  $300\Omega$  should be provided between pins 4 and 6. No other biasing provisions are required.
  - (3) The maximum AC load current can be increased by adding an external resistor between pins 1 and 7. The minimum value for this resistor is  $800\Omega$ , giving a maximum load current of  $4mA_{rms}$ .

### 2. EXTERNAL DECOUPLING AND MOUNTING CONSIDERATIONS.

- a. All decoupling capacitors should be ceramic type with minimum residual inductance at the operating frequency.
- b. Decoupling capacitor leads at pins 5, 6, and 12 should be as short as possible.
- c. Connections from pin 4 should be as far removed as possible from connections at pins 9, 10, and 12.
- d. The power supply pin 13 should be decoupled with a  $0.1\mu F$  ceramic capacitor, keeping the leads as short as possible.
- e. When using a large internal impedance power supply (voltage dropping resistor), decouple pin 13 for the lowest audio demodulation frequency.
- f. Keep appropriate distances between the input coil and any other coil in the phase shift network for the voltage gain between these points is high (40 to 60dB).

## TEST CIRCUITS

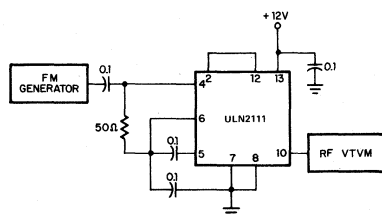


FIGURE 1

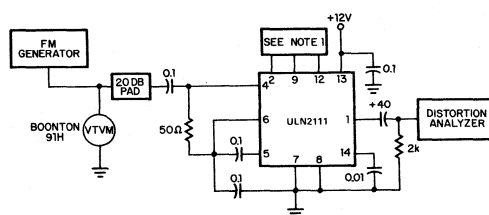


FIGURE 2

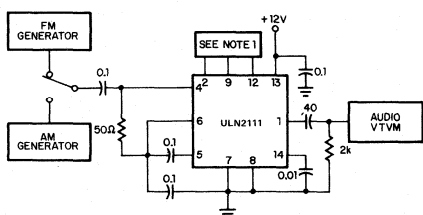
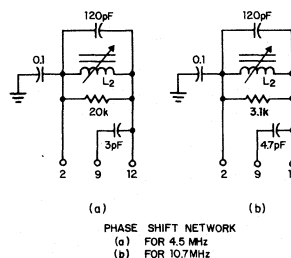


FIGURE 3



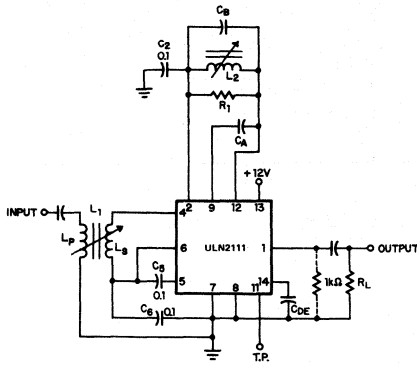
PHASE SHIFT NETWORK  
(a) FOR 4.5 MHz  
(b) FOR 10.7 MHz

FIGURE 4

NOTES: 1. Phase shift network is specified in Figure 4. 2. All capacitors in microfarads unless otherwise noted.

APPLICATIONS

TYPICAL CIRCUIT REQUIREMENTS FOR FM DETECTION



	Component Value		Notes
	TV (4.5MHz)	FM (10.7MHz)	
L <sub>2</sub> Inductance	7 - 14μH	1.5 - 3μH	1
L <sub>2</sub> Nom. Unloaded Q	50	50	
L <sub>2</sub> Nom. DC Resistance	50Ω	50Ω	
CA	3.0pF	4.7pF	2
CB	120pF	120pF	
R <sub>1</sub>	20kΩ	3.1kΩ	
Loaded Network Q	30	20	
C <sub>5</sub> and C <sub>6</sub>	0.1μF	0.1μF	
C <sub>2</sub>	0.1μF	0.1μF	
C <sub>de</sub>	0.01μF	0.01μF	

NOTES:

1. Suggested coil source: 1.5 - 3μH Miller 9050, 7 - 14μH Miller 9052.
2. Use NPO type capacitor.

Figure 5

TYPICAL DRIVING CAPABILITIES at f<sub>o</sub> = 4.5MHz

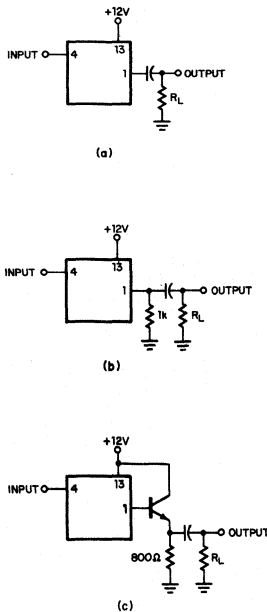
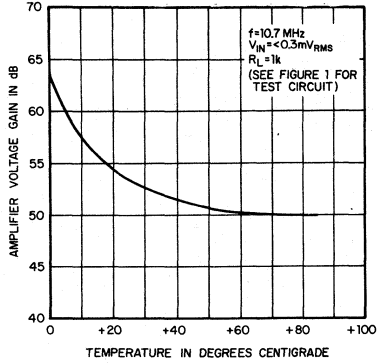


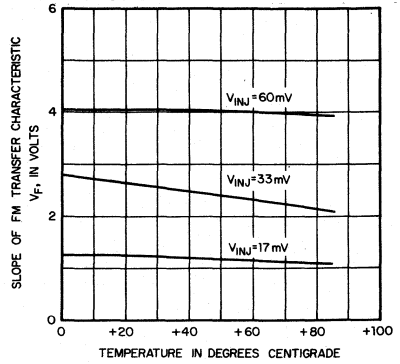
Figure	R <sub>L</sub> (Ω)	V <sub>o</sub> (mV <sub>rms</sub> )		Remarks
		Δf = 7.5 kHz	Δf = 25 kHz	
A	2000	220	650	No Clipping
B	200	130	400	No Clipping
C	200	220	650	Clipping at V <sub>o</sub> = 500mV <sub>rms</sub>

Figure 6

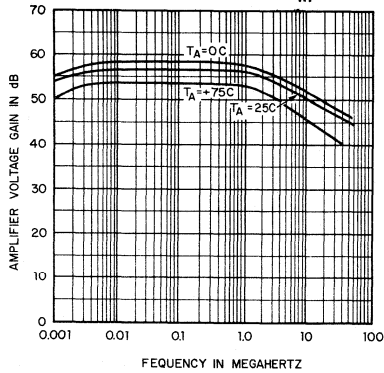
AMPLIFIER GAIN AS A FUNCTION OF AMBIENT TEMPERATURE



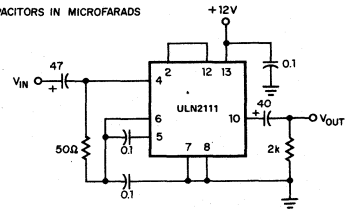
SLOPE OF FM TRANSFER CHARACTERISTICS AS A FUNCTION OF AMBIENT TEMPERATURE



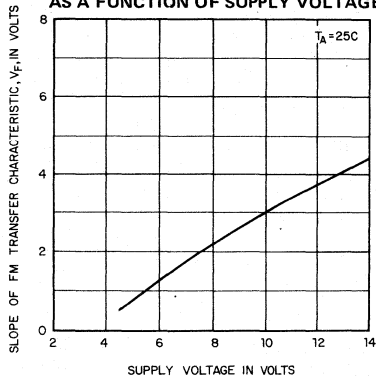
AMPLIFIER VOLTAGE GAIN AS A FUNCTION OF OPERATING FREQUENCY AT  $V_{in} = 0.2 \text{ mV}_{ms}$



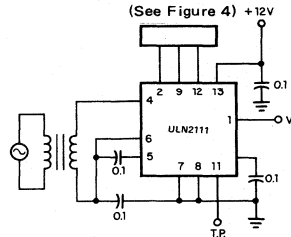
ALL CAPACITORS IN MICROFARADS



SLOPE OF FM TRANSFER CHARACTERISTIC AS A FUNCTION OF SUPPLY VOLTAGE



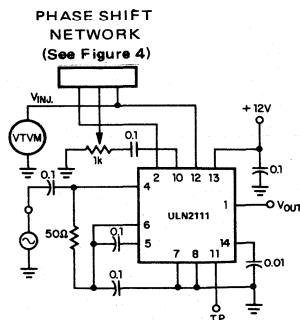
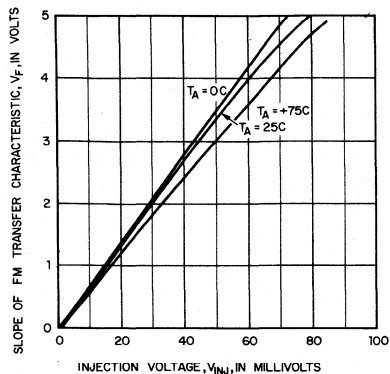
PHASE SHIFT NETWORK (See Figure 4)



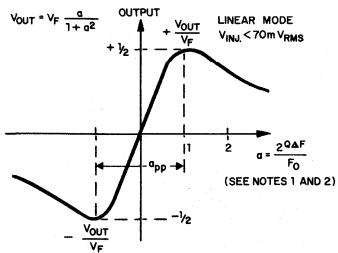
ALL CAPACITORS IN MICROFARADS

TYPICAL CHARACTERISTIC CURVES (Cont'd.)

SLOPE OF FM TRANSFER CHARACTERISTICS AS A FUNCTION OF INJECTION VOLTAGE



TRANSFER CHARACTERISTICS FOR A SIMPLE LC NETWORK



OUTPUT = f (NORMALIZED DEVIATION)  
 (The units along the vertical axis are arbitrary units.)  
 Linear mode: Operation of the FM detector with no limiting after the phase shift network.

NOTES:

1.  $V_f$  defines the slope of the FM transfer characteristic, at origin:

$$V_f = \frac{dV_{out}}{da} \quad a = 0$$

$V_f$  is primarily a function of bias current in the detector and injection voltage.

$V_f$  will decrease with decreasing  $V_{CC}$  or  $V_{INJ}$ .

2.  $a$  = normalized frequency deviation:

$$a = \frac{2Q\Delta F}{F_0}$$

## PRELIMINARY SPECIFICATION

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The MC1310/MC1310E are integrated FM stereo demodulators using phase locked loop technology to regenerate the 38KHz Subcarrier. The device features a wide operating voltage, 8–16Vdc and a low external parts count.

### FEATURES

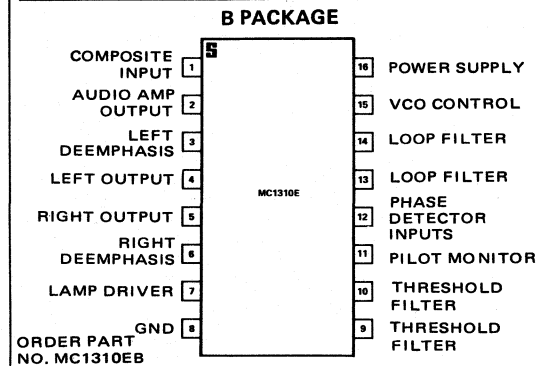
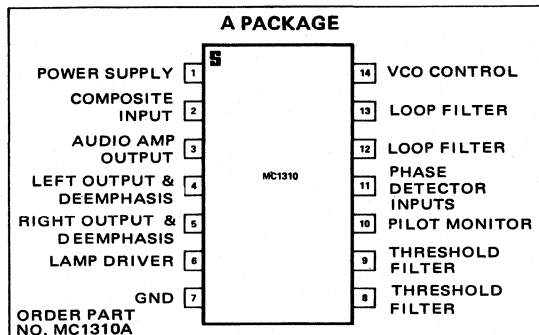
- NO INDUCTORS REQUIRED
- INTEGRAL STEREO/MONAUROUS SWITCH
- 75mA LAMP DRIVING CAPABILITY
- EXCELLENT SCA REJECTION
- WIDE SUPPLY RANGE: 8-16Vdc
- EXCELLENT CHANNEL SEPARATION
- EMITTER FOLLOWER OUTPUTS (MC1310E)

### ABSOLUTE MAXIMUM RATINGS

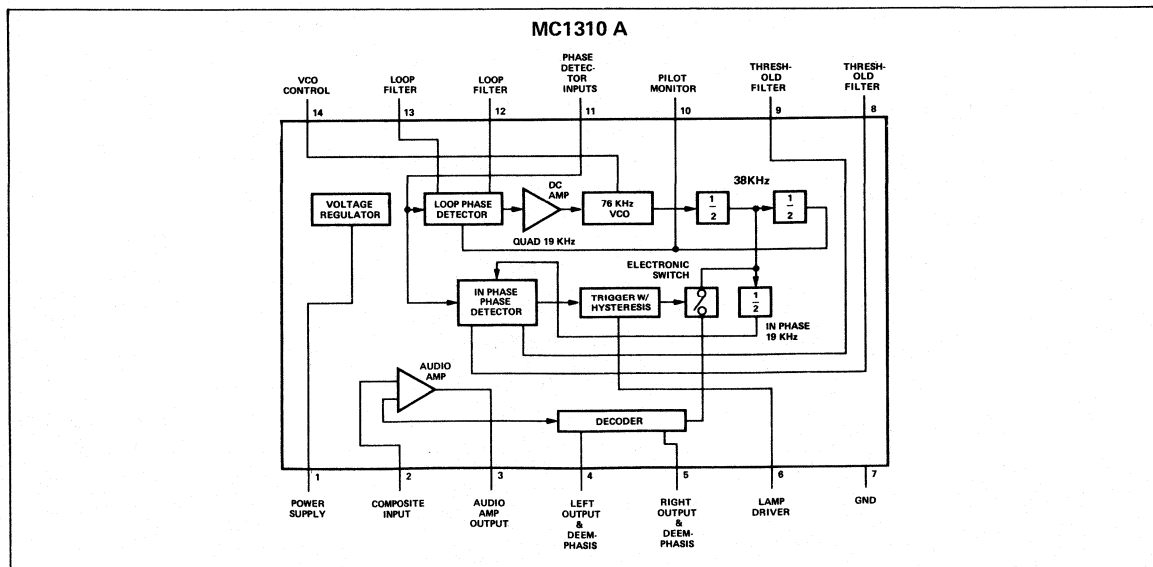
Supply Voltage	16 Volts
Lamp Current (12V lamp)	75 mA
Power Dissipation*	625 mW
Operating temperature range	-30°C to +85°C
Storage temperature range	-65°C to +150°C

\*Derate at 5 mW/°C above 25°C

### PIN CONFIGURATIONS (Top View)

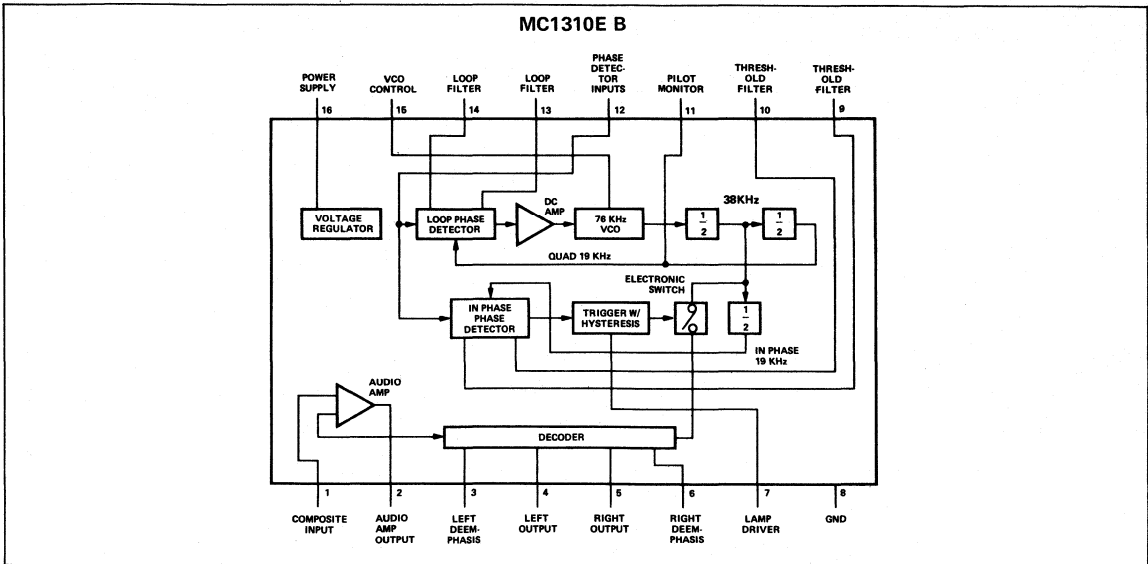


### BLOCK DIAGRAMS





BLOCK DIAGRAMS (Cont'd.)

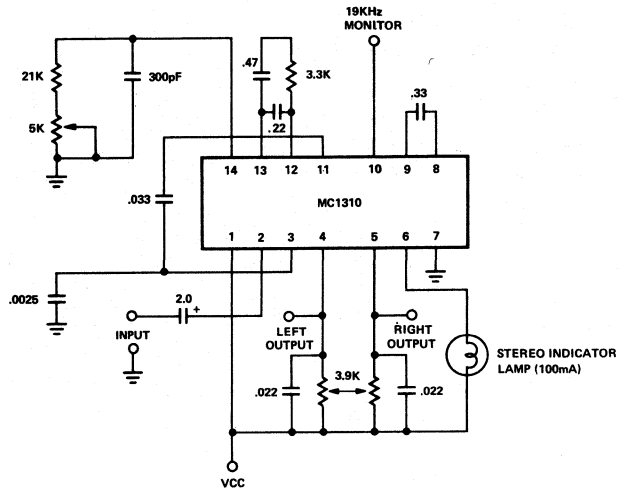


ELECTRICAL CHARACTERISTICS  $V+ = 12Vdc, T_A = 25^{\circ}C$

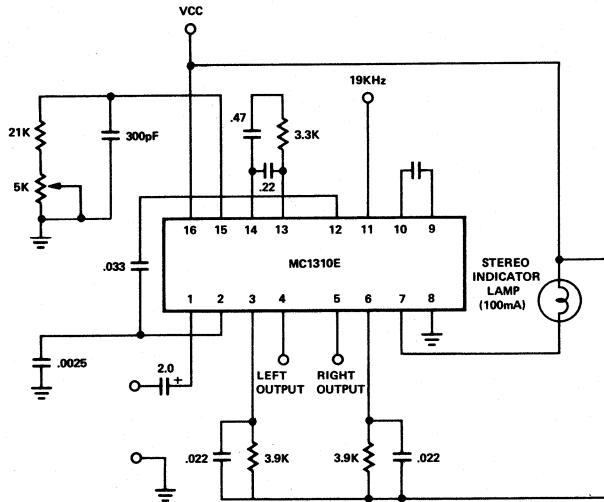
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Supply Current MC1310E	Lamp off		22	30	mA
MC1310	Lamp off		19	30	mA
Maximum Standard Composite Input Signal (0.5% THD)		2.8			$V_{p-p}$
Maximum Monaural Input Signal (1.0% THD)		2.8			$V_{p-p}$
Input Impedance			50		$k\Omega$
Stereo Channel Separation (50Hz - 15KHz)		30	40		dB
Audio Output Voltage (Desired Channel)			485		mV RMS
Monaural Channel Balance (Pilot Tone "OFF")				1.5	dB
Total Harmonic Distortion			.3		%
Ultrasonic Frequency Rejection					
19KHz			34.4		dB
38KHz			45		dB
Inherent SCA Rejection (f = 67KHz; 9.0KHz Beat Note Measured With 1.0KHz Modulation Off)			80		dB
Stereo (19KHz Input Level for Lamp "On")		12	16	20	mV RMS
Hysteresis			6		dB
Capture Range			$\pm 3$		%
Supply Voltage		8		16	Vdc

TYPICAL APPLICATIONS

MC1310



MC1310E



#### DESCRIPTION

The 5556 is an internally compensated precision monolithic operational amplifier featuring extremely low offset and bias currents and offset null capability. The 5556 is short circuit protected and its high common mode and differential input voltage range provides exceptional performance when used as an integrator, summing amplifier, and voltage follower.

The 5556 features industry standard pinout and is a direct pin-for-pin replacement for the MC1556G and MC1456G.

#### ABSOLUTE MAXIMUM RATINGS

Power Supply Voltage

S5556	±22V
N5556	±18V

Differential Input Voltage

± V+

Common Mode Input Voltage

± V+

Load Current

20mA

Output Short Circuit Duration

Indefinite

Power Dissipation

680mW

Derate Above T<sub>A</sub> = 25°C

4.6mW/°C

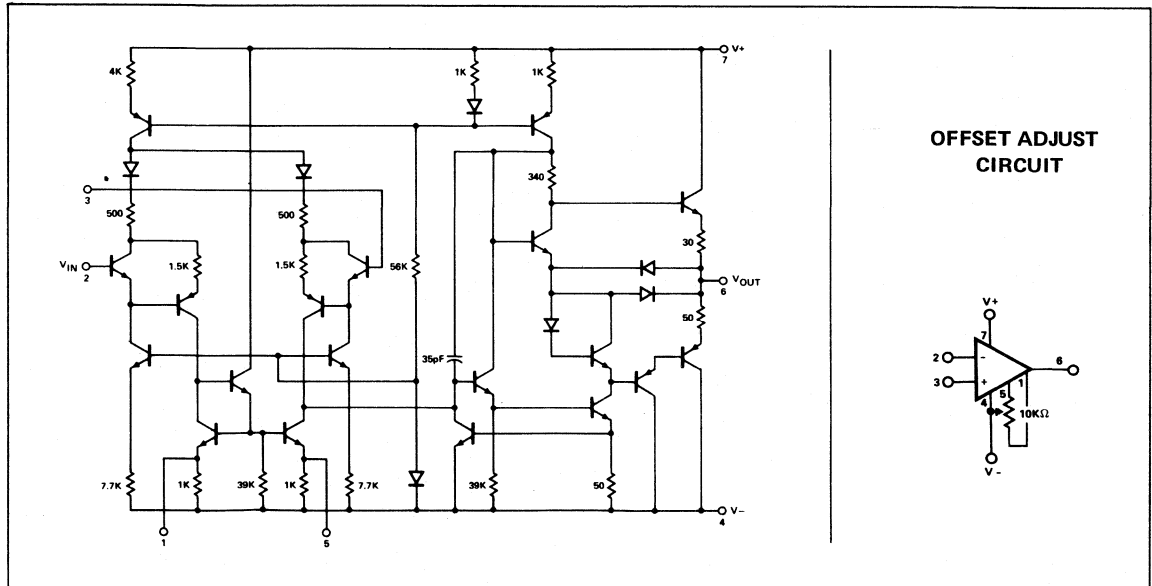
Operating Temperature Range

S5556	-55°C to +125°C
N5556	0°C to +70°C

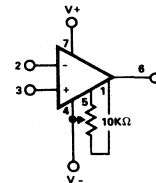
Storage Temperature Range

-65°C to +150°C

#### EQUIVALENT CIRCUIT



#### OFFSET ADJUST CIRCUIT

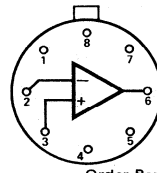


#### FEATURES

- LOW INPUT BIAS CURRENT - 15nA maximum
- LOW INPUT OFFSET CURRENT - 2.0nA maximum
- LOW INPUT OFFSET VOLTAGE - 4.0mV maximum
- HIGH SLEW RATE - 2.5 V/μs typical
- LARGE POWER BANDWIDTH - 40kHz typical
- LOW POWER CONSUMPTION - 45mW maximum
- OFFSET VOLTAGE NULL CAPABILITY

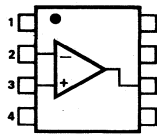
#### PIN CONFIGURATIONS (Top View)

##### T PACKAGE



Order Part Nos. S5556T/N5556T

##### V PACKAGE



Order Part Nos. S5556V/N5556V

**SIGNETICS HIGH PERFORMANCE OPERATIONAL AMPLIFIER ■ MC1556, MC1456**

**ELECTRICAL CHARACTERISTICS ( $V^+ = +15V$ ,  $V^- = -15V$ ,  $T_A = +25^\circ C$  Unless Otherwise Noted)**

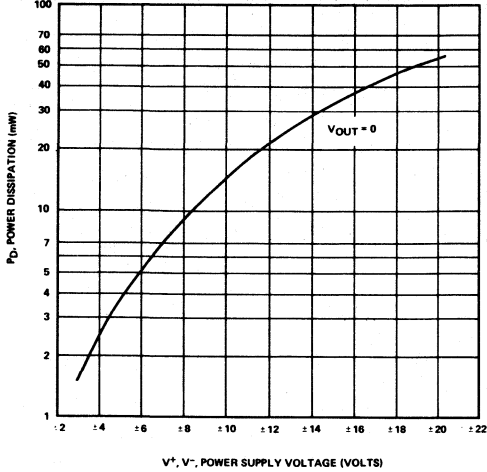
PARAMETER	SYMBOL	MIN		TYP		MAX		UNITS
		S5556	N5556	S5556	N5556	S5556	N5556	
Input Bias Current $T_A = 25^\circ C$ $T_A = T_{LOW}$ to $T_{HIGH}$ (Note 1)	$I_B$	1556	1456	1556	1456	1556	1456	nA nA
Input Offset Current $T_A = 25^\circ C$ $T_A = 25^\circ C$ to $T_{High}$ $T_A = T_{LOW}$ to $25^\circ C$	$I_{io}$			1.0	5.0	2.0	10	nA nA nA
Input Offset Voltage $T_A = 25^\circ C$ $T_A = T_{LOW}$ to $T_{HIGH}$	$V_{io}$			2.0	5.0	4.0	10	mV mV
Differential Input Impedance (Open Loop— $f = 20Hz$ ) Parallel Input Resistance Parallel Input Capacitance	$R_p$ $C_p$			5.0	3.0			Meg $\Omega$ pF
Common Mode Input Impedance ( $f = 20Hz$ )	$Z_{IN}$			250	250			Meg $\Omega$
Common Mode Input Voltage Swing	$CMV_{IN}$	$\pm 12$	$\pm 11$	$\pm 13$	$\pm 12$			V
Equivalent Input Noise Voltage  ( $A_v = 100$ , $R_s = 10K\Omega$ , $F = 1.0KHz$ , $BW = 1.0Hz$ )	$E_{IN}$			45	45			nV/ $\sqrt{Hz}$
Common Mode Rejection Ratio ( $f = 100Hz$ )	CMRR	80	70	110	110			dB
Open Loop Voltage Gain ( $V_{OUT} = \pm 10V$ , $R_L = 2K\Omega$ $T_A = 25^\circ C$ $T_A = T_{LOW}$ to $T_{HIGH}$ )	$A_{VO}$	100K 40K	70K 40K	200K	100K			V/V V/V
Power Bandwidth $A_v = 1$ , $R_L = 2K\Omega$ , THD $\leq 5\%$ , $V_{OUT} = \pm 10V$ )	$P_{BW}$			40	40			KHz
Unity Gain Crossover Frequency (open-loop)				1.0	1.0			MHz
Phase Margin (open-loop, unity gain)				70	70			Degrees
Gain Margin				18	18			dB
Slew Rate (unity gain)	$dV_{OUT}/dt$			2.5	2.5			V/ $\mu sec$
Output Impedance ( $f = 20Hz$ )	$Z_{OUT}$			1.0	1.0	2.0	2.5	K $\Omega$
Output Voltage Swing ( $R_L = 2K\Omega$ )	$V_{OUT}$	$\pm 12$	$\pm 11$	$\pm 13$	$\pm 12$			V
Power Supply Sensitivity $V^- = \text{Constant}$ , $R_S \leq 10K$ $V^+ = \text{Constant}$ , $R_S \leq 10K$	$S^+$ $S^-$			50	75	100	200	$\mu V/V$ $\mu V/V$
Power Supply Current	$I_{D+}$ $I_{D-}$			1.0	1.3	1.5	3.0	mA mA
DC Quiescent Power Dissipation ( $V_{OUT} = 0$ )	$P_D$			30	40	45	90	mW

NOTE:

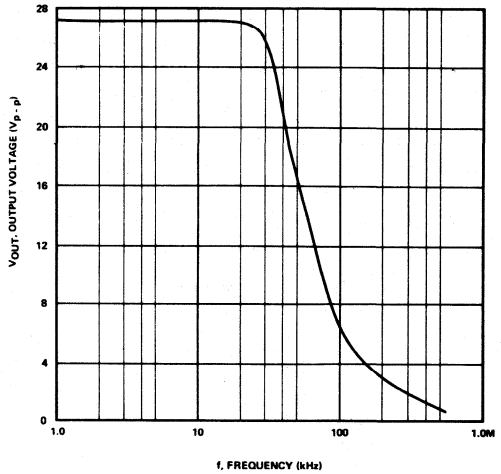
1.  $T_{LOW} = 0^\circ C$  for N5556,  $-55^\circ C$  for S5556;  $T_{HIGH} = 70^\circ C$  for N5556,  $125^\circ C$  for S5556

TYPICAL PERFORMANCE CHARACTERISTICS

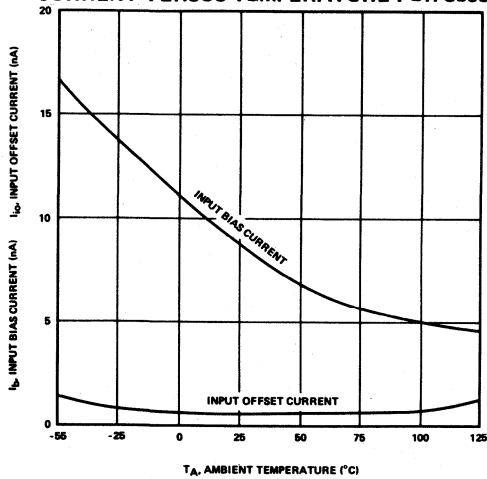
POWER DISSIPATION VERSUS POWER SUPPLY VOLTAGE



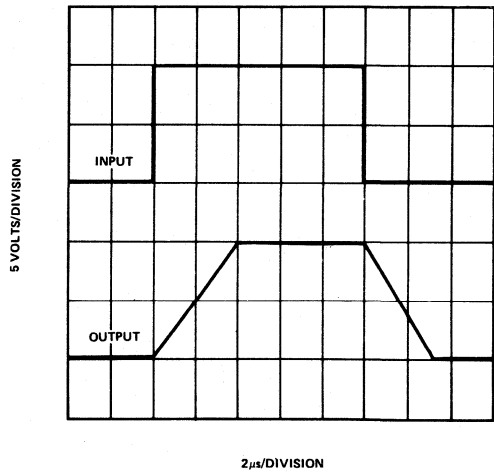
POWER BANDWIDTH



TYPICAL INPUT BIAS CURRENT AND INPUT OFFSET CURRENT VERSUS TEMPERATURE FOR S5556



VOLTAGE-FOLLOWER PULSE RESPONSE



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 5558 consists of a pair of high performance monolithic operational amplifiers constructed on a single chip. It features internal compensation and is intended for use in a variety of analog applications. High common mode voltage range and immunity to latch-up makes the 5558 ideal for use as a voltage follower. The high gain and wide range of operating voltage achieves superior performance in integrator, summing amplifier, and general feedback applications. The device is short-circuit protected. For single amplifier performance see the 5741 data sheet. The 5558 is a pin-for-pin replacement for the MC1558G.

### ABSOLUTE MAXIMUM RATINGS

#### Power Supply Voltages

S5558	±22V
N5558	±18V

#### Differential Input Voltage

	±30V
--	------

#### Common-mode Input Swing

	±15V
--	------

#### Output Short Circuit Duration

	Continuous
--	------------

#### Power Dissipation (Note 1)

T Package — (MO-002-AG)	680mW
V Package	625mW

#### Operating Temperature Range

S5558	-55°C to +125°C
N5558	0°C to +75°C

#### Storage Temperature Range

	-65°C to +150°C
--	-----------------

#### Lead Temperature (Soldering, 60 sec)

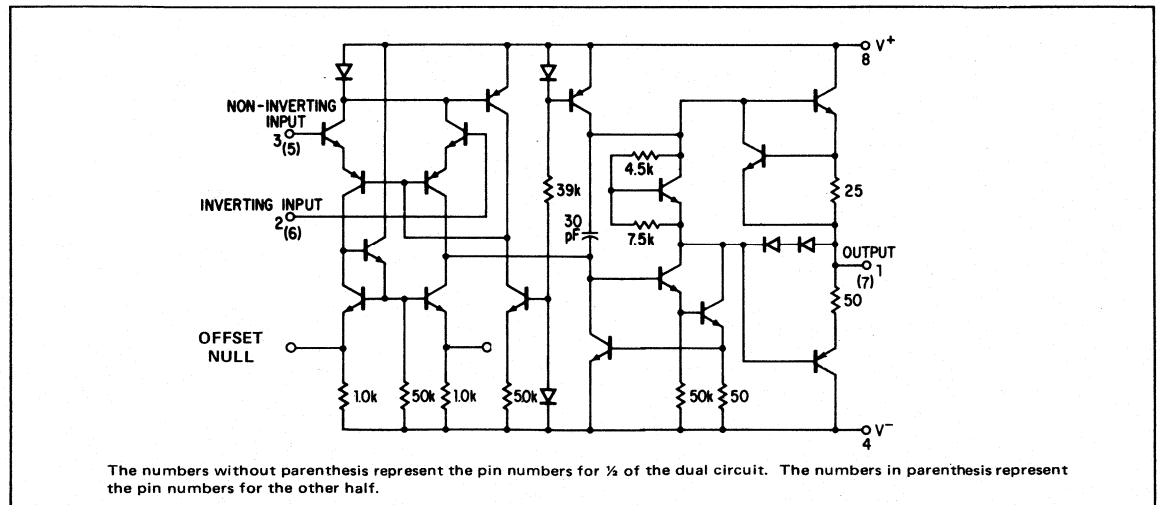
	300°C
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#### NOTE:

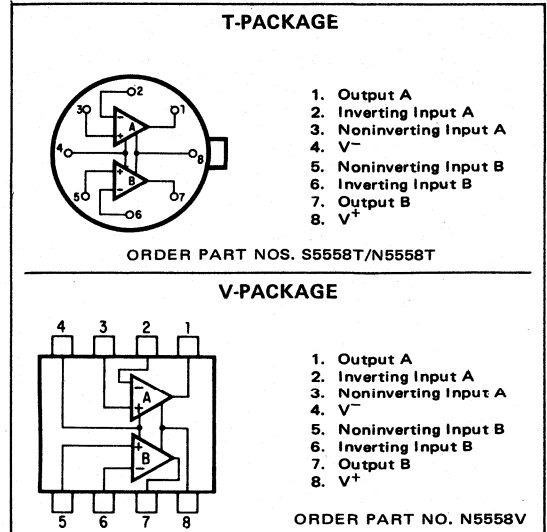
1. Derate T package linearly at 4.6 mW/°C for ambient temperatures above +25°C

2. Derate V package at 5mW/°C above 25°C

### EQUIVALENT SCHEMATIC



### PIN CONFIGURATIONS (TOP VIEW)



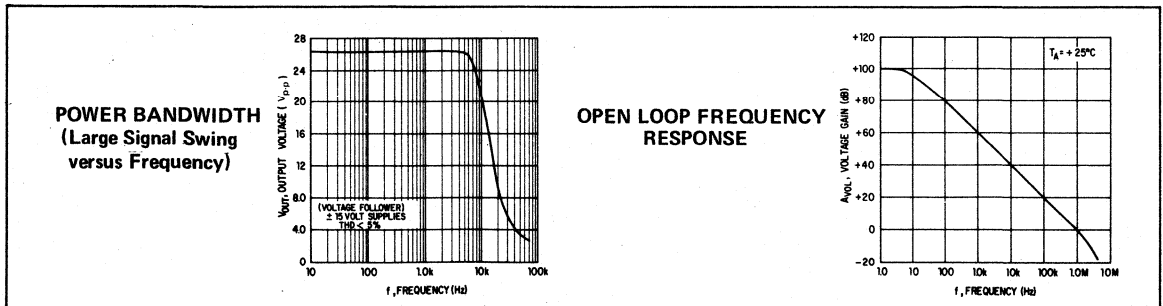
**SIGNETICS DUAL OPERATIONAL AMPLIFIERS ■ MC1558, MC1458**

**ELECTRICAL CHARACTERISTICS** ( $V^+ = +15\text{ Vdc}$ ,  $V^- = -15\text{ Vdc}$ ,  $T_A = +25^\circ\text{C}$  unless otherwise noted)

CHARACTERISTICS	SYMBOL	MIN		TYP		MAX		UNIT
		S5558	N5558	S5558	N5558	S5558	N5558	
Input Bias Current $T_A = +25^\circ\text{C}$ $T_A = T_{\text{low}}$ to $T_{\text{high}}$ (See Note 1)	$I_b$	1558	1458	1558	1458	1558	1458	$\mu\text{A}$
Input Offset Current $T_A = +25^\circ\text{C}$ $T_A = T_{\text{low}}$ to $T_{\text{high}}$	$I_{\text{io}}$			0.03	0.03	0.2	0.2	$\mu\text{A}$
Input Offset Voltage ( $R_S \leq 10\text{k}\Omega$ ) $T_A = +25^\circ\text{C}$ $T_A = T_{\text{low}}$ to $T_{\text{high}}$	$V_{\text{io}}$			1.0	2.0	5.0	6.0	mV
Differential Input Impedance (Open-Loop, $f = 20\text{ Hz}$ )						6.0	7.5	
Parallel Input Resistance	$R_p$	0.3	0.3	1.0	1.0			Megohm
Parallel Input Capacitance	$C_p$			6.0	6.0			pF
Common-Mode Input Impedance ( $f = 20\text{ Hz}$ )	$Z_{\text{(in)}}$			200	200			Megohms
Common-Mode Input Voltage Swing	$CMV_{\text{in}}$	$\pm 12$	$\pm 12$	$\pm 13$	$\pm 13$			V <sub>pk</sub>
Equivalent Input Noise Voltage ( $A_V = 100$ , $R_S = 10\text{k}\Omega$ $f = 1.0\text{ kHz}$ , $BW = 1.0\text{ Hz}$ )	$e_n$			45	45			nV(Hz) <sup>1/2</sup>
Common-Mode Rejection Ratio ( $f = 100\text{ Hz}$ )	$CM_{\text{rej}}$	70	70	90	90			dB
Open-Loop Voltage Gain, ( $V_{\text{out}} = \pm 10\text{V}$ , $R_L = 2.0\text{k}\Omega$ ) $T_A = +25^\circ\text{C}$ $T_A = T_{\text{low}}$ to $T_{\text{high}}$	$AV_{\text{OL}}$	50,000	20,000	200,000	100,000			V/V
Power Bandwidth ( $A_V = 1$ , $R_L = 2.0\text{k}\Omega$ , $\text{THD} \leq 5\%$ , $V_{\text{out}} = 20\text{V}_{\text{p-p}}$ )	PBW	25,000	15,000	14	14			kHz
Unity Gain Crossover Frequency (open-loop)				1.1	1.1			MHz
Phase Margin (open-loop, unity gain)				65	65			degrees
Gain Margin				11	11			dB
Slew Rate (Unity Gain)	$dV_{\text{out}}/dt$			0.8	0.8			V/ $\mu\text{s}$
Output Impedance ( $f = 20\text{ Hz}$ )	$Z_{\text{out}}$			300	300			ohms
Short-Circuit Output Current	$I_{\text{SC}}$			20	20			mA
Output Voltage Swing ( $R_L = 10\text{k}\Omega$ ) $R_L = 2\text{k}\Omega$ ( $T_A = T_{\text{low}}$ to $T_{\text{high}}$ )	$V_{\text{out}}$	$\pm 12$ $\pm 10$	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$	$\pm 14$ $\pm 13$			V <sub>pk</sub>
Power Supply Sensitivity $V^- = \text{constant}$ , $R_S \leq 10\text{k}\Omega$ $V^+ = \text{constant}$ , $R_S \leq 10\text{k}\Omega$	$S^+$ $S^-$			30 30	30 30	150 150	150 150	$\mu\text{V/V}$
Power Supply Current	$I_{\text{D}}^+$ $I_{\text{D}}^-$			2.3 2.3	2.3 2.3	5.0 5.0	5.6 5.6	mA
DC Quiescent Power Dissipation ( $V_{\text{out}} = 0$ )	$P_{\text{D}}$			70	70	150	170	mW
Channel Separation	$e_{\text{O1}}/e_{\text{O2}}$			120	120			dB

Note 1:  $T_{\text{low}} = 0^\circ\text{C}$  for N5558,  $-55^\circ\text{C}$  for S5558;  $T_{\text{high}} = +75^\circ\text{C}$  for N5558,  $+125^\circ\text{C}$  for S5558

**TYPICAL CHARACTERISTIC CURVES**



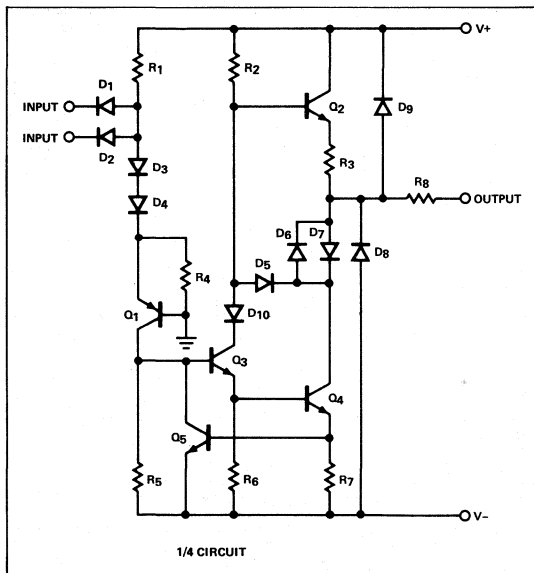
### DESCRIPTION

The MC1488 is a quad line driver which converts standard DTL/TTL input logic levels through one stage of inversion to output levels which meet EIA Standard No. RS-232C and CCITT Recommendation V. 24.

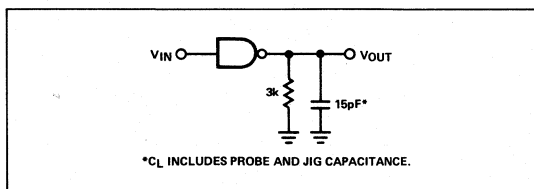
### FEATURES

- CURRENT LIMITED OUTPUT:  $\pm 10\text{mA TYP}$
- POWER-OFF SOURCE IMPEDANCE:  $300\Omega \text{ MIN}$
- SIMPLE SLEW RATE CONTROL WITH EXTERNAL CAPACITOR
- FLEXIBLE OPERATING SUPPLY RANGE
- INPUTS ARE DTL/TTL COMPATIBLE

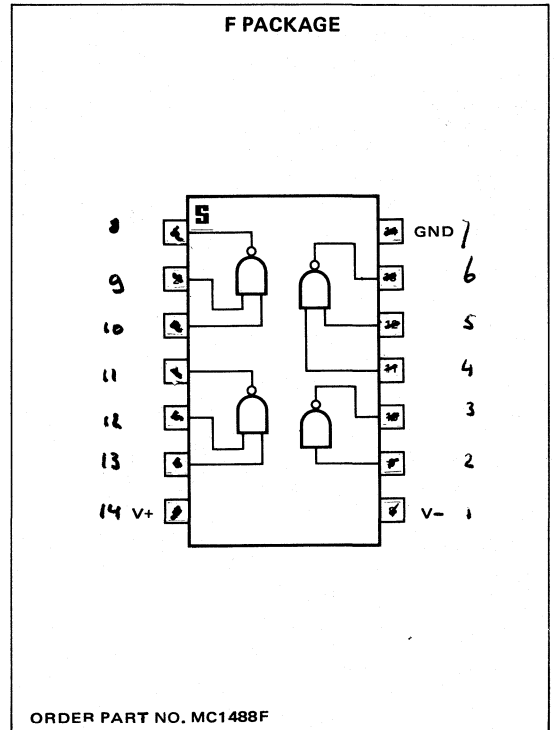
### CIRCUIT SCHEMATIC



### AC LOAD CIRCUIT



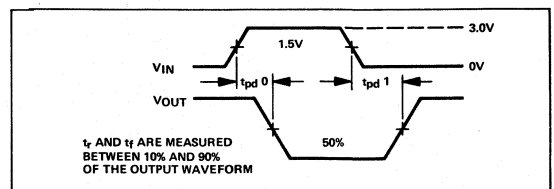
### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS (Note 1)

Supply Voltage $V^+$	+15V
$V^-$	-15V
Input Voltage ( $V_{IN}$ )	$-15V \leq V_{IN} \leq 7.0V$
Output Voltage	$\pm 15V$
Power Dissipation	1000mW
Operating Temperature Range	$0^\circ\text{C to } +75^\circ\text{C}$
Storage Temperature Range	$-65^\circ\text{C to } +175^\circ\text{C}$
Lead Temperature (Soldering, 10 sec)	$300^\circ\text{C}$

### SWITCHING WAVEFORMS





## ELECTRICAL CHARACTERISTICS (Note 2)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS	
Logic "0" Input Current	$V_{IN} = 0V$		-1.0	-1.3	mA	
Logic "1" Input Current	$V_{IN} = +5.0V$		.005	10.0	$\mu A$	
High Level Output Voltage	$R_L = 3.0k\Omega$ $V_{IN} = 0.8V$	$V^+ = 9.0V$ $V^- = -9.0V$	6.0	7.0	V	
		$V^+ = 13.2V$ $V^- = -13.2V$	9.0	10.5	V	
Low Level Output Voltage	$R_L = 3.0k\Omega$ $V_{IN} = 1.9V$	$V^+ = 9.0V$ $V^- = -9.0V$	-6.0	-6.8	V	
		$V^+ = 13.2V$ $V^- = -13.2V$	-9.0	-10.5	V	
High Level Output Short-Circuit Current	$V_{OUT} = 0V$ $V_{IN} = 0.8V$	-6.0	-10.0	-12.0	mA	
Low Level Output Short-Circuit Current	$V_{OUT} = 0V$ $V_{IN} = 1.9V$	6.0	10.0	12.0	mA	
Output Resistance	$V^+ = V^- = 0V$ $V_{OUT} = \pm 2V$	300			$\Omega$	
Positive Supply Current (Output Open)	$V_{IN} = 1.9V$	$V^+ = 9.0V, V^- = -9.0V$		15.0	20.0	mA
		$V^+ = 12V, V^- = -12V$		19.0	25.0	mA
		$V^+ = 15V, V^- = -15V$		25.0	34.0	mA
	$V_{IN} = 0.8V$	$V^+ = 9.0V, V^- = -9.0V$		4.5	6.0	mA
		$V^+ = 12V, V^- = -12V$		5.5	7.0	mA
		$V^+ = 15V, V^- = -15V$		8.0	12.0	mA
Negative Supply Current (Output Open)	$V_{IN} = 1.9V$	$V^+ = 9.0V, V^- = -9.0V$		-13.0	-17.0	mA
		$V^+ = 12V, V^- = -12V$		-18.0	-23.0	mA
		$V^+ = 15V, V^- = -15V$		-25.0	-34.0	mA
	$V_{IN} = 0.8V$	$V^+ = 9.0V, V^- = -9.0V$		-.001	-1.0	mA
		$V^+ = 12V, V^- = -12V$		-.001	-1.0	mA
		$V^+ = 15V, V^- = -15V$		-.01	-2.5	mA
Power Dissipation	$V^+ = 9.0V, V^- = -9.0V$ $V^+ = 12V, V^- = -12V$		252 444	333 576	mW mW	
Propagation Delay to "1" ( $t_{pd1}$ )	$R_L = 3.0k\Omega, C_L = 15pF, T_A = 25^\circ C$		230	300	ns	
Propagation Delay to "0" ( $t_{pd0}$ )	$R_L = 3.0k\Omega, C_L = 15pF, T_A = 25^\circ C$		70	175	ns	
Rise Time ( $t_r$ )	$R_L = 3.0k\Omega, C_L = 15pF, T_A = 25^\circ C$		75	100	ns	
Fall Time ( $t_f$ )	$R_L = 3.0k\Omega, C_L = 15pF, T_A = 25^\circ C$		40	75	ns	

## NOTES

- Voltage values shown are with respect to network ground terminal. Positive current is defined as current into the referenced pin.
- These specifications apply for  $V^+ = +9.0V \pm 1\%$ ,  $V^- = -9.0V \pm 1\%$ ,  $T_A = 0^\circ C$  to  $+75^\circ C$  unless otherwise noted. All typicals are for  $V^+ = 9.0V$ ,  $V^- = -9.0V$ , and  $T_A = 25^\circ C$ .

APPLICATIONS

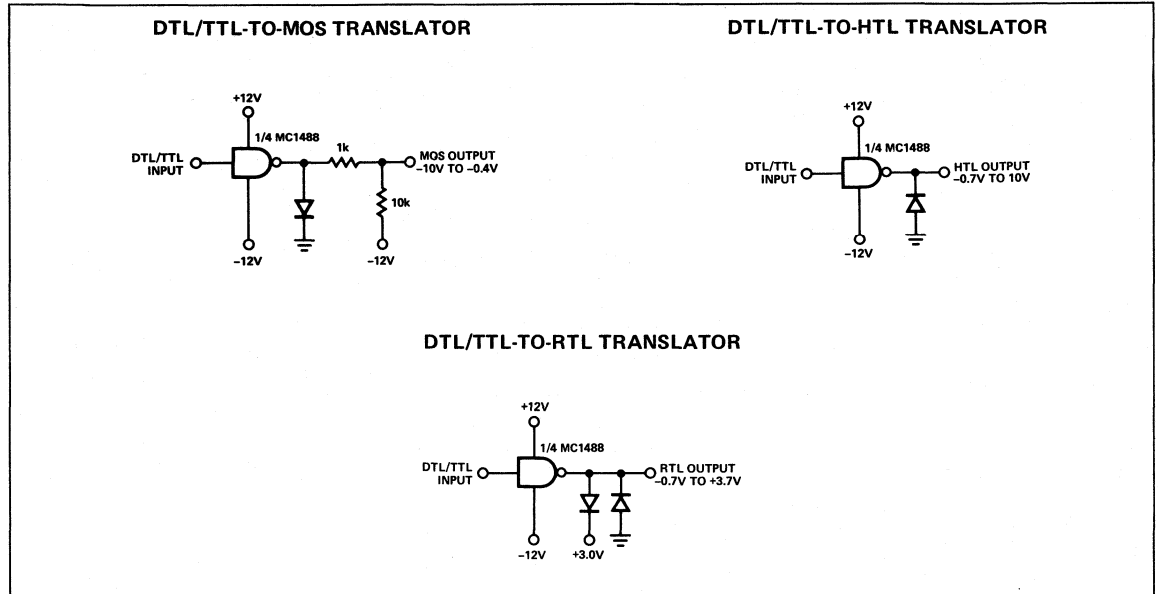
By connecting a capacitor to each driver output the slew rate can be controlled utilizing the output current limiting characteristics of the MC1488. For a set slew rate the appropriate capacitor value may be calculated using the following relationship

$$C = I_{SC} (\Delta T / \Delta V)$$

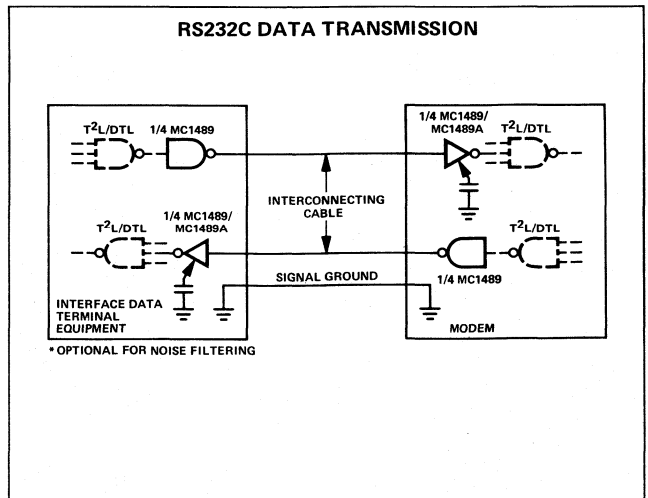
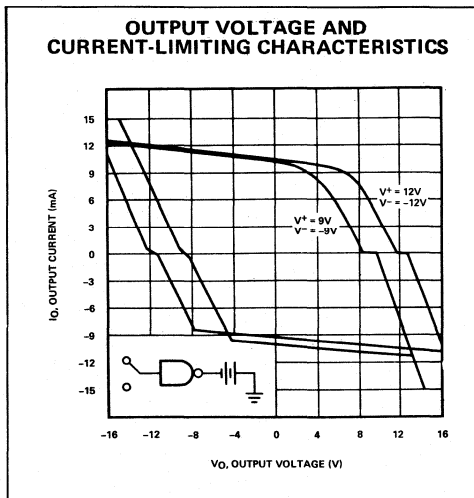
where C is the required capacitor,  $I_{SC}$  is the short circuit current value, and  $\Delta V / \Delta T$  is the slew rate.

RS232C specifies that the output slew rate must not exceed 30V per microsecond. Using the worst case output short circuit current of 12mA in the above equation, calculations result in a required capacitor of 400pF connected to each output.

TYPICAL APPLICATIONS



CHARACTERISTIC CURVES



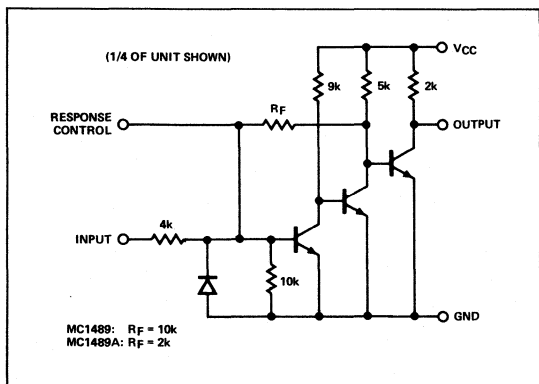
### DESCRIPTION

The MC1489/MC1489A are quad line receivers designed to interface data terminal equipment with data communications equipment. They are constructed on a single monolithic silicon chip. These devices satisfy the specifications of EIA standard No. RS232C.

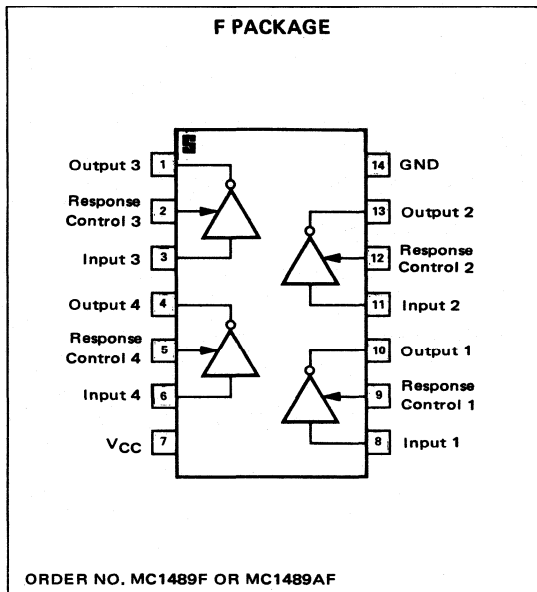
### FEATURES

- FOUR TOTALLY SEPARATE RECEIVERS PER PACKAGE
- PROGRAMMABLE THRESHOLD
- BUILT-IN INPUT THRESHOLD HYSTERESIS
- "FAIL SAFE" OPERATING MODE
- INPUTS WITHSTAND  $\pm 30V$

### CIRCUIT SCHEMATIC



### PIN CONFIGURATION (Top View)

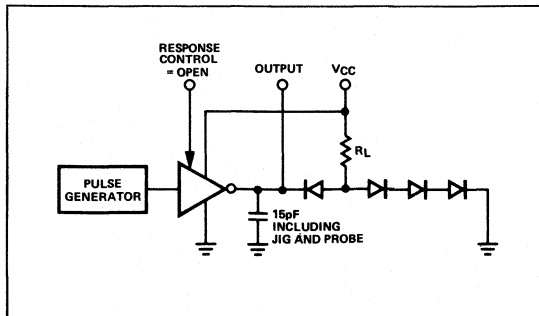


### ABSOLUTE MAXIMUM RATINGS (Note 1)

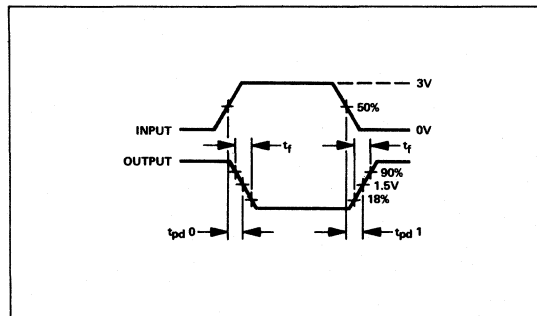
The following apply for  $T_A = 25^\circ C$  unless otherwise specified.

Power Supply Voltage	10V
Input Voltage Range	$\pm 30V$
Output Load Current	20mA
Power Dissipation	1W
Operating Temperature Range	$0^\circ C$ to $+75^\circ C$
Storage Temperature Range	$-65^\circ C$ to $+175^\circ C$

### AC TEST CIRCUIT



### VOLTAGE WAVEFORMS



# SIGNETICS QUAD LINE RECEIVER ■ MC1489, MC1489A

**ELECTRICAL CHARACTERISTICS** MC1489/MC1489A  $V_{CC} = 5.0V \pm 1\%$ ,  $0^{\circ}C \leq T_A \leq +75^{\circ}C$  unless otherwise specified. (Note 2)

PARAMETER	CONDITIONS	MC1489			MC1489A			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Input High Threshold Voltage	$T_A = 25^{\circ}C$ , $V_{OUT} \leq 0.45V$ , $I_{OUT} = 10mA$	1.0		1.5	1.75		2.25	V
Input Low Threshold Voltage	$T_A = 25^{\circ}C$ , $V_{OUT} \leq 2.5V$ , $I_{OUT} = -0.5mA$	0.75		1.25	0.75		1.25	V
Input Current	$V_{IN} = +25V$	+3.6	+5.6	+8.3	+3.6	+5.6	+8.3	mA
	$V_{IN} = -25V$	-3.6	-5.6	-8.3	-3.6	-5.6	-8.3	
	$V_{IN} = +3V$	+0.43	+0.53		+0.43	+0.53		mA
	$V_{IN} = -3V$	-0.43	-0.53		-0.43	-0.53		
Output High Voltage	$V_{IN} = 0.75V$ , $I_{OUT} = -0.5mA$	2.6	3.8	5.0	2.6	3.8	5.0	V
	Input = Open, $I_{OUT} = -0.5mA$	2.6	3.8	5.0	2.6	3.8	5.0	V
Output Low Voltage	$V_{IN} = 3.0V$ , $I_{OUT} = 10mA$		0.33	0.45		0.33	0.45	V
Output Short Circuit Current	$V_{IN} = 0.75V$		3.0			3.0		mA
Supply Current	$V_{IN} = 5.0V$		20	26		20	26	mA
Power Dissipation	$V_{IN} = 5.0V$		100	130		100	130	mW

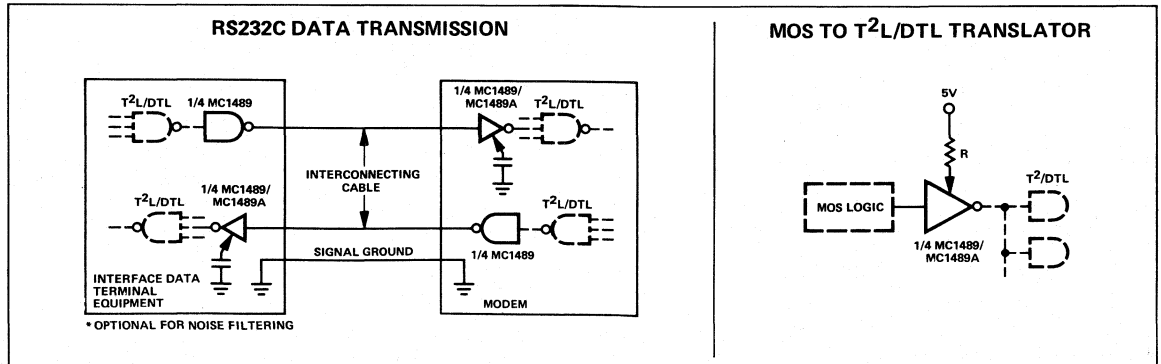
**ELECTRICAL CHARACTERISTICS** MC1489/MC1489A  $V_{CC} = 5.0V \pm 1\%$ ,  $T_A = 25^{\circ}C$

PARAMETER	CONDITIONS	MC1489			MC1489A			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Input to Output "High" Propagation Delay ( $t_{pd1}$ )	$R_L = 3.9k$ (AC Test Circuit)		25	85		25	85	ns
Input to Output "Low" Propagation Delay ( $t_{pd0}$ )	$R_L = 390\Omega$ (AC Test Circuit)		20	50		20	50	ns
Output Rise Time	$R_L = 3.9k$ (AC Test Circuit)		110	175		110	175	ns
Output Fall Time	$R_L = 390\Omega$ (AC Test Circuit)		9	20		9	20	ns

**NOTES**

1. Voltage values shown are with respect to network ground terminal. Positive current is defined as current into the referenced pin.
2. These specifications apply for response control pin = open.

**TYPICAL APPLICATIONS**



### DESCRIPTION

The 5596 is a monolithic Double-Balanced Modulator/Demodulator designed for use where the output voltage is a product of an input voltage (signal) and a switched function (carrier). The S5596 will operate over the full military temperature range of  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ . The N5596 is intended for applications within the range of  $0^{\circ}\text{C}$  to  $+70^{\circ}\text{C}$ .

### FEATURES

- EXCELLENT CARRIER SUPPRESSION

65dB typ @ 0.5 MHz

50dB typ @ 10 MHz

- ADJUSTABLE GAIN AND SIGNAL HANDLING
- BALANCED INPUTS AND OUTPUTS
- HIGH COMMON-MODE REJECTION — 85dB typ

### APPLICATIONS

SUPPRESSED CARRIER AND AMPLITUDE  
MODULATION

SYNCHRONOUS DETECTION

FM DETECTION

PHASE DETECTION

SAMPLING

SINGLE SIDEBAND

FREQUENCY DOUBLING

### ABSOLUTE MAXIMUM RATINGS

Applied Voltage (Note 1)	30V
Differential Input Signal ( $V_7 - V_8$ )	$\pm 5.0\text{V}$
Differential Input Signal ( $V_4 - V_1$ )	$\pm(5 + I_5 R_0)\text{V}$
Input Signal ( $V_2 - V_1, V_3 - V_4$ )	5.0V
Bias Current ( $I_5$ )	10mA
Power Dissipation (Pkg. Limitation)	

K-Package	680mW
Derate above $25^{\circ}\text{C}$	5.4mW/ $^{\circ}\text{C}$

A-Package (TO-116)	900mW
Derate above $25^{\circ}\text{C}$	7.2mW/ $^{\circ}\text{C}$

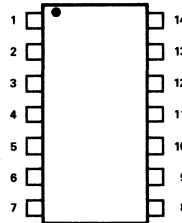
Operating Temperature Range	$-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
Storage Temperature Range	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$

### NOTES:

1. Voltage applied between pins 6-7, 8-1, 9-7, 9-8, 7-4, 7-1, 8-4, 6-8, 2-5, 3-5.
2. Pin number references pertain to K package pinout only.

### PIN CONFIGURATIONS (TOP VIEW)

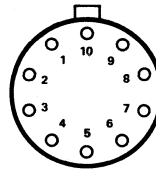
#### A PACKAGE



1. Positive Signal Input
2. Gain Adjust
3. NC
4. Gain Adjust
5. Negative Signal Input
6. Bias
7. NC
8. Positive Output
9. Positive Carrier Input
10. Negative Carrier Input
11. NC
12. NC
13. Negative Output
14.  $V^-$

ORDER PART NOS.  
S5596A/N5596A

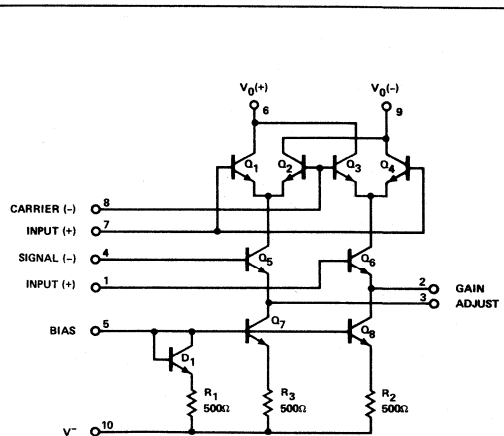
#### K PACKAGE



1. Positive Signal Input
2. Gain Adjust
3. Gain Adjust
4. Negative Signal Input
5. Bias
6. Positive Output
7. Positive Carrier Input
8. Negative Carrier Input
9. Negative Output
10.  $V^-$

ORDER PART NOS.  
S5596K/N5596K

### SCHEMATIC DIAGRAM



# SIGNETICS BALANCED MODULATOR-DEMODULATOR ■ MC1596, MC1496

## ELECTRICAL CHARACTERISTICS\* (All input and output characteristics are single-ended unless otherwise noted.)

PARAMETER	MC1596			MC1496			UNITS
	MIN	TYP	MAX	MIN	TYP	MAX	
Carrier Feedthrough $V_C = 60$ mV(rms) sine wave and offset adjusted to zero $f_C = 1.0$ kHz $f_C = 10$ MHz		40 140			40 140		$\mu$ V (rms)
$V_C = 300$ mVp-p square wave: offset adjusted to zero offset not adjusted $f_C = 1.0$ kHz $f_C = 1.0$ kHz		0.04 20	0.2 100		0.04 20	0.4 200	mV (rms)
Carrier Suppressions $f_S = 10$ kHz, 300 mV(rms) $f_C = 500$ kHz, 60 mV(rms) sine wave $f_C = 10$ MHz, 60 mV(rms) sine wave	50	65 50		40	65 50		dB
Transadmittance Bandwidth (Magnitude) ( $R_L = 50\Omega$ ) Carrier Input Port, $V_C = 60$ mV(rms) sine wave $f_S = 1.0$ kHz; 300 mV(rms) sine wave Signal Input Port, $V_S = 300$ mV(rms) sine wave $ V_C  = 0.5$ V dc		300 80			300 80		MHz
Signal Gain $V_S = 100$ mV(rms), $f = 1.0$ kHz; $ V_C  = 0.5$ V dc	2.5	3.5		2.5	3.5		V/V
Single-Ended Input Impedance, Signal Port, $f = 5.0$ MHz Parallel Input Resistance Parallel Input Capacitance		200 2.0			200 2.0		$k\Omega$ pF
Single-Ended Output Impedance, $f = 10$ MHz Parallel Output Resistance Parallel Output Capacitance		40 5.0			40 5.0		$k\Omega$ pF
Input Bias Current $I_{bS} = \frac{I_1 + I_4}{2}$ ; $I_{bC} = \frac{I_7 + I_8}{2}$		12 12	25 25		12 12	30 30	$\mu$ A
Input Offset Current $I_{ioS} = I_1 - I_4$ ; $I_{ioC} = I_7 - I_8$		0.7 0.7	5.0 5.0		0.7 0.7	7.0 7.0	$\mu$ A
Average Temperature Coefficient of Input Offset Current ( $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ )		2.0			2.0		$\text{nA}/^\circ\text{C}$
Output Offset Current ( $I_6 - I_9$ )		14	50		15	80	$\mu$ A
Average Temperature Coefficient of Output Offset Current ( $T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$ )		90			90		$\text{nA}/^\circ\text{C}$
Common-Mode Input Swing, Signal Port, $f_S = 1.0$ kHz		5.0			5.0		Vp-p
Common-Mode Gain, Signal Port, $f_S = 1.0$ kHz, $ V_C  = 0.5$ V dc		-85			-85		dB
Common-Mode Quiescent Output Voltage (Pin 6 or Pin 9)		8.0			8.0		Vdc
Differential Output Voltage Swing Capability		8.0			8.0		Vp-p
Power Supply Current $I_6 + I_9$ $I_{10}$		2.0 3.0	3.0 4.0		2.0 3.0	4.0 5.0	mAdc
DC Power Dissipation		33			33		mW

( $V^+ = +12$ V dc,  $V^- = -8.0$ V dc,  $I_5 = 1.0$ mA dc,  $R_L = 3.9$ k $\Omega$ ,  $R_e = 1.0$ k $\Omega$ ,  $T_A = +25^\circ\text{C}$  unless otherwise noted)

\*Pin number references pertain to K package pinout only.

### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

The 7520 Series Dual Core Memory Sense Amplifiers are designed for use in high speed core memory systems. Three separate logic configurations allow flexibility of system design.

The 7520 and 7521 can be used to perform the function of a flip-flop or a data register which responds to the sense and strobe-input conditions.

The 7522 and 7523 features an open collector stage which may be used to perform the wired-OR function.

The 7524 and 7525 features two independent sense channels with separate outputs.

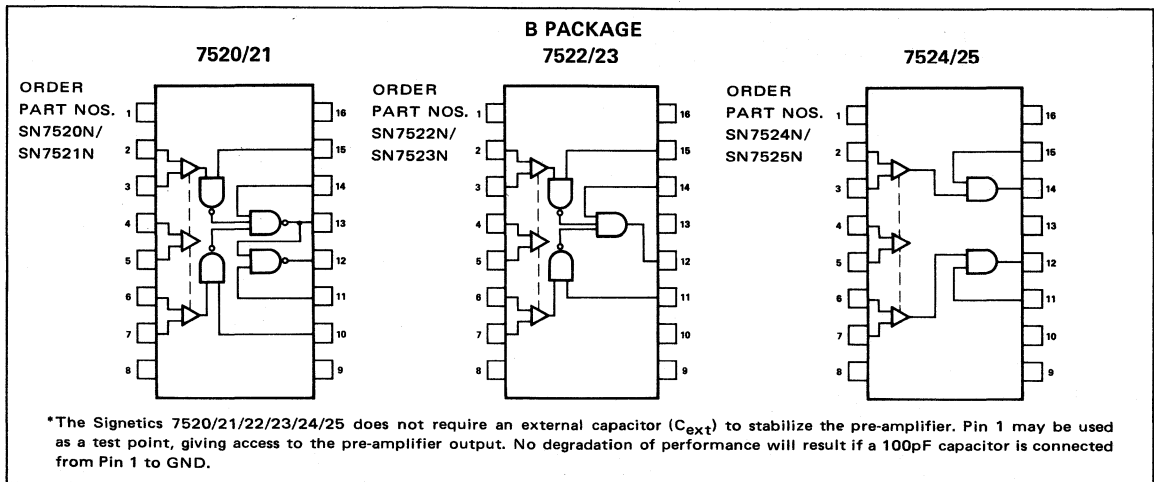
#### FEATURES

- DUAL SENSE AMPS
- $\pm 4\text{mV}$  THRESHOLD UNCERTAINTY
- DESIGN VERSATILITY
- 25ns PROPAGATION DELAY

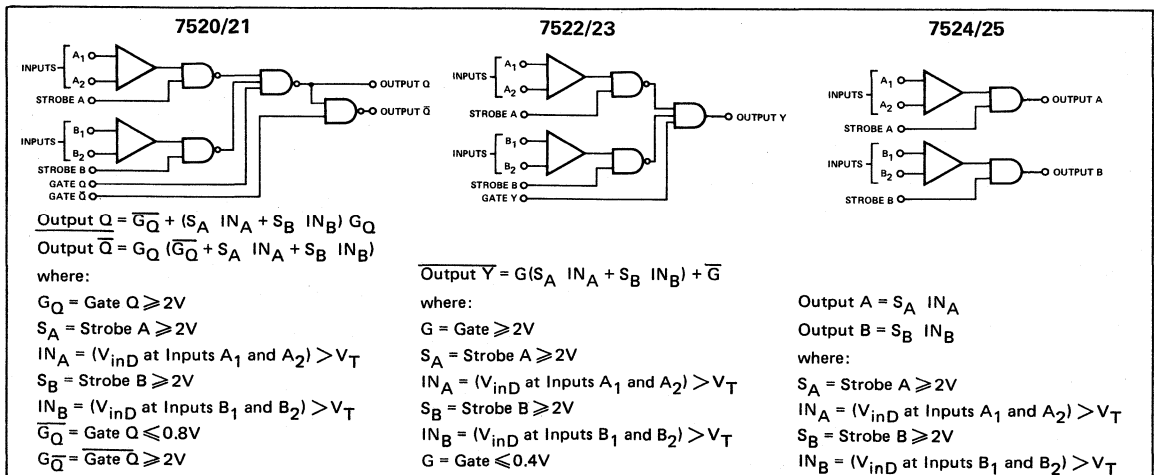
#### ABSOLUTE MAXIMUM RATINGS

Differential Input Voltage	$\pm 5\text{V}$
$V_{CC}$	$\pm 7\text{V}$
Strobe & Gain Input Voltages	$+5.5\text{V}$
Storage Temperature	$-65^\circ\text{C}$ to $+150^\circ\text{C}$
Operating Temperature	$0^\circ\text{C}$ to $+70^\circ\text{C}$
Power Dissipation	500mW

#### PIN CONFIGURATIONS (TOP VIEW)



#### LOGIC DIAGRAMS



**SIGNETICS DUAL CORE MEMORY SENSE AMPLIFIERS ■ SN7520/21/22/23/24/25**

**ELECTRICAL CHARACTERISTICS** ( $V_{cc1} = 5V$ ,  $V_{cc2} = -5V$ ,  $T_A = 0^\circ C$  to  $+70^\circ C$ , unless otherwise specified)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNITS	
$V_T$	Differential-Input Threshold Voltage (See Note 1)	$V_{ref} = 15mV$	7520	11	15	18	mV
			7521	8	15	22	mV
		$V_{ref} = 40mV$	7520	36	40	44	mV
			7521	33	40	47	mV
$V_{CMF}$	Common-Mode Input Firing Voltage (See Note 2)	Strobe Input: $V_{inS} = V_{in(1)}$ Common-Mode Input Pulse: $t_r = t_f \leq 15ns$ , $t_p(in) = 50ns$ $T_A = 25^\circ C$		$\pm 3$		V	
$I_{in}$	Differential-Input Bias Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{inD} = 0mV$		30	75	$\mu A$	
$I_{DI}$	Differential-Input Offset Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$		0.5		$\mu A$	
$z_{inD}$	Differential-Input Impedance	$f = 1 kHz$		2		$k\Omega$	
$V_{in(1)}$	Logical 1 Input Voltage (gate and strobe inputs)	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{in(0)} = 0.8V$	2			V	
$V_{in(0)}$	Logical 0 Input Voltage (gate and strobe inputs)	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{in(1)} = 2V$			0.8	V	
$I_{in(0)}$	Logical 0 Level Input Current (gate and strobe inputs)	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(0)} = 0.4V$			-1.6	mA	
$I_{in(1)}$	Logical 1 Level Input Current (gate and strobe inputs)	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(1)} = 2.4V$ $V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$			40	$\mu A$	
		$V_{in(1)} = V_{cc1}$			1	mA	
$V_{out(1)}$	Logical 1 Output Voltage	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $I_{load} = -400\mu A$	2.4	3.9		V	
$V_{out(0)}$	Logical 0 Output Voltage	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $I_{sink} = 16mA$		0.25	0.4	V	
$I_{OS(Q)}$	Q Output Short-Circuit Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$	3.3		5	mA	
$I_{OS(Q)}$	Q Output Short-Circuit Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$	2.1		3.5	mA	
$I_{cc1}$	$V_{cc1}$ Supply Current	$T_A = 25^\circ C$		28		mA	
$I_{cc2}$	$V_{cc2}$ Supply Current	$T_A = 25^\circ C$		-14		mA	
$t_{or D}$	Differential-Input Overload Recovery Time (See Note 3)	$V_{inD} = 2V$ , $t_r = t_f = 20ns$		20		ns	
$t_{or CM}$	Common-Mode Input Overload Recovery Time (See Note 4)	$V_{inCM} = 2V$ , $t_r = t_f = 20ns$		20		ns	
$t_{cyc(min)}$	Minimum cycle time			200		ns	

PROPAGATION DELAY TIMES			MIN	TYP	MAX	UNIT
SYMBOL	FROM INPUT	TO OUTPUT				
$t_{pd(1)DQ}$ , $t_{pd(0)DQ}$	$A_1 - A_2$ or $B_1 - B_2$	Q		20	40	ns
		$\bar{Q}$		30		ns
$t_{pd(1)D\bar{Q}}$ , $t_{pd(0)D\bar{Q}}$	$A_1 - A_2$ or $B_1 - B_2$	Q		25		ns
		$\bar{Q}$		35	55	ns
$t_{pd(1)SQ}$ , $t_{pd(0)SQ}$	Strobe A or B	Q		15	30	ns
		$\bar{Q}$		25		ns
$t_{pd(1)S\bar{Q}}$ , $t_{pd(0)S\bar{Q}}$	Strobe A or B	Q		15		ns
		$\bar{Q}$		35	55	ns
$t_{pd(1)G_QQ}$ , $t_{pd(0)G_QQ}$	Gate Q	Q		10	20	ns
		$\bar{Q}$		15		ns
$t_{pd(1)G_Q\bar{Q}}$ , $t_{pd(0)G_Q\bar{Q}}$	Gate Q	Q		15		ns
		$\bar{Q}$		20	30	ns
$t_{pd(1)G_{\bar{Q}}Q}$ , $t_{pd(0)G_{\bar{Q}}Q}$	Gate $\bar{Q}$	Q		15		ns
		$\bar{Q}$		10	20	ns

(SEE NOTES PAGE 128)



**SIGNETICS DUAL CORE MEMORY SENSE AMPLIFIERS ■ SN7520/21/22/23/24/25**

**ELECTRICAL CHARACTERISTICS** ( $V_{cc1} = 5V$ ,  $V_{cc2} = -5V$ ,  $T_A = 0^\circ C$  to  $+70^\circ C$ , unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$V_T$	Differential Input Threshold Voltage (See Note 1)	$V_{ref} = 15mV$	7522	11	15	19	mV
			7523	8	15	22	mV
		$V_{ref} = 40mV$	7522	36	40	44	mV
			7523	33	40	47	mV
$V_{CMF}$	Common Mode Input Firing Voltage (See Note 2)	Strobe Input: $V_{inS} = V_{in(1)}$ Common Mode Input Pulse: $t_r = t_f \geq 15ns$ , $t_{p(in)} = 50ns$ $T_A = 25^\circ C$			$\pm 3$		V
$I_{in}$	Differential Input Bias Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{inD} = 0mV$			30	75	$\mu A$
$I_{DI}$	Differential Input Offset Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$			0.5		$\mu A$
$z_{inD}$	Differential Input Impedance	$f = 1 kHz$			2		k $\Omega$
$V_{in(1)}$	Logical 1 Input Voltage (gate and strobe inputs)	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{in(0)} = 0.8V$		2			V
$V_{in(0)}$	Logical 0 Input Voltage (gate and strobe inputs)	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{in(1)} = 2V$				0.8	V
$I_{in(0)}$	Logical 0 Level Input Current (gate and strobe inputs)	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(0)} = 0.4V$			-1	-1.6	mA
$I_{in(1)}$	Logical 1 Level Input Current (gate and strobe inputs)	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(1)} = 2.4V$				40	$\mu A$
		$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(1)} = V_{cc1}$				1	mA
$V_{out(1)}$	Logical 1 Output Voltage	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $I_{load} = -400\mu A$ , $V_{in} = 2V$		2.4	3.9		V
$V_{out(0)}$	Logical 0 Output Voltage	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $I_{sink} = 16mA$ , $V_{in} = 0.8V$			0.2	0.4	V
$I_{out(1)}$	Output Reverse Current	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{out} = 5.25V$ , $V_{in} = 2V$				250	$\mu A$
$I_{OS}$	Output Short Circuit Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$		2.1		3.5	mA
$I_{cc1}$	$V_{cc1}$ Supply Current	$T_A = 25^\circ C$			27		mA
$I_{cc2}$	$V_{cc2}$ Supply Current	$T_A = 25^\circ C$			15		mA
$t_{orD}$	Differential Input Overload Recovery Time (See Note 3)	$V_{inD} = 2V$ , $t_r = t_f = 20ns$			20		ns
$t_{orCM}$	Common Mode Input Overload Recovery Time (See Note 4)	$V_{inCM} = \pm 2V$ , $t_r = t_f = 20ns$			20		ns
$t_{cyc(min)}$	Minimum Cycle Time				200		ns

PROPAGATION DELAY TIMES			MIN	TYP	MAX	UNIT
SYMBOL	FROM INPUT	TO OUTPUT				
$t_{pd(1)D}$	$A_1 - A_2$ or $B_1 - B_2$	Y		20		ns
$t_{pd(0)D}$				30	45	ns
$t_{pd(1)S}$	Strobe A or B	Y		15		ns
$t_{pd(0)S}$				25	40	ns
$t_{pd(1)G}$	Gate	Y		10		ns
$t_{pd(0)G}$				15	25	ns

(SEE NOTES PAGE 128)

# SIGNETICS DUAL CORE MEMORY SENSE AMPLIFIERS ■ SN7520/21/22/23/24/25

## ELECTRICAL CHARACTERISTICS ( $V_{cc1} = 5V$ , $V_{cc2} = -5V$ , $T_A = 0^\circ C$ to $+70^\circ C$ , unless otherwise specified)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
$V_T$	Differential Input Threshold Voltage (See Note 1)	$V_{ref} = 15mV$	7524	11	15	19	mV
			7525	8	15	22	mV
		$V_{ref} = 40mV$	7524	36	40	44	mV
			7525	33	40	47	mV
$V_{CMF}$	Common Mode Input Firing Voltage (See Note 2)	Strobe Input: $V_{inS} = V_{in(1)}$ Common Mode Input Pulse: $t_r = t_f \leq 15ns$ , $t_{p(in)} = 50ns$ $T_A = 25^\circ C$		$\pm 3$		V	
$I_{in}$	Differential Input Bias Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{inD} = 0mV$		30	75	$\mu A$	
$I_{DI}$	Differential Input Offset Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $f = 1kHz$		0.5		$\mu A$	
$z_{inD}$	Differential Input Impedance			2		k $\Omega$	
$V_{in(1)}$	Logical 1 Input Voltage (strobe inputs)	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{in(0)} = 0.8V$	2			V	
$V_{in(0)}$	Logical 0 Input Voltage (strobe inputs)	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $V_{in(1)} = 2V$			0.8	V	
$I_{in(0)}$	Logical 0 Level Input Current (strobe inputs)	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(0)} = 0.4V$		-1	-1.6	mA	
$I_{in(1)}$	Logical 1 Level Input Current (strobe inputs)	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(1)} = 2.4V$			40	$\mu A$	
		$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$ $V_{in(1)} = V_{cc1}$			1	mA	
$V_{out(1)}$	Logical 1 Output Voltage	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $I_{load} = -400\mu A$ , $V_{in(1)} = 2V$ $V_{in(0)} = 0.8V$	2.4	3.9		V	
$V_{out(0)}$	Logical 0 Output Voltage	$V_{cc1} = 4.75V$ , $V_{cc2} = -4.75V$ $I_{sink} = 16mA$ , $V_{in(0)} = 0.8V$		0.25	0.4	V	
$I_{OS}$	Output Short Circuit Current	$V_{cc1} = 5.25V$ , $V_{cc2} = -5.25V$	2.1		3.5	mA	
$I_{cc1}$	$V_{cc1}$ Supply Current	$T_A = 25^\circ C$		25		mA	
$I_{cc2}$	$V_{cc2}$ Supply Current	$T_A = 25^\circ C$		-15		mA	
$t_{orD}$	Differential Input Overload Recovery Time (See Note 3)	$V_{inD} = 2V$ , $t_r = t_f = 20ns$		20		ns	
$t_{orCM}$	Common Mode Input Overload Recovery Time (See Note 4)	$V_{inCM} = \pm 2V$ , $t_r = t_f = 20ns$		20		ns	
$t_{cyc(min)}$	Minimum Cycle Time			200		ns	

PROPAGATION DELAY TIMES			MIN	TYP	MAX	UNIT
SYMBOL	FROM INPUT	TO OUTPUT				
$t_{pd(1)D}$	$A_1 - A_2$ or $B_1 - B_2$	A or B	25	40		ns
$t_{pd(0)D}$			20			ns
$t_{pd(1)S}$	Strobe A or B	A or B	15	30		ns
$t_{pd(0)S}$			20			ns

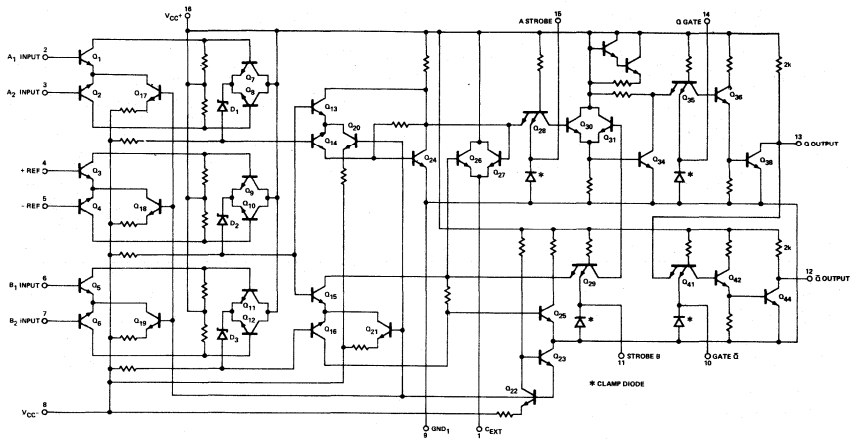
### NOTES:

- The differential input threshold voltage ( $V_T$ ) is defined as the DC input voltage ( $V_{in}$ ) required to force the output of the sense amplifier to the logic gate threshold voltage level.
- Common mode input firing voltage is the common mode voltage that will exceed the dynamic range of the input at the specified conditions and cause the logic output to switch. The specified common mode input signal is applied with a strobe enable signal present.
- Differential input overload recovery time is the time necessary for the device to recover from the specified differential input overload signal prior to the strobe enable signal.
- Common mode input overload recovery time is the time necessary for the device to recover from the specified common mode input overload signal prior to the strobe enable signal.

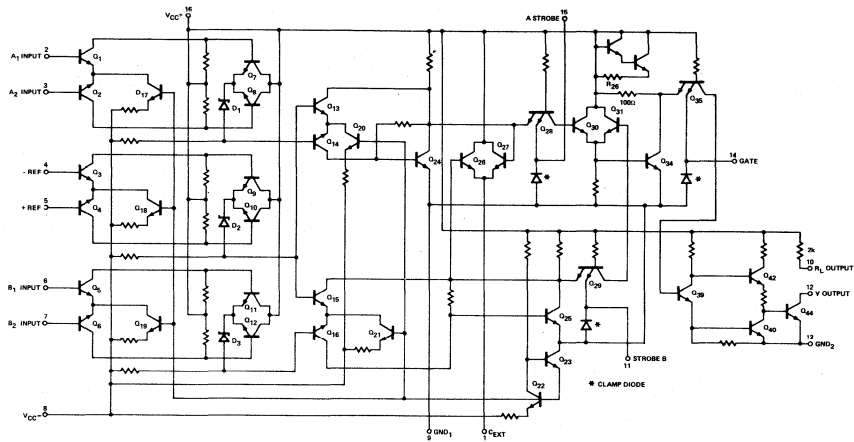
SIGNETICS DUAL CORE MEMORY SENSE AMPLIFIERS ■ SN7520/21/22/23/24/25

SCHEMATIC DIAGRAMS

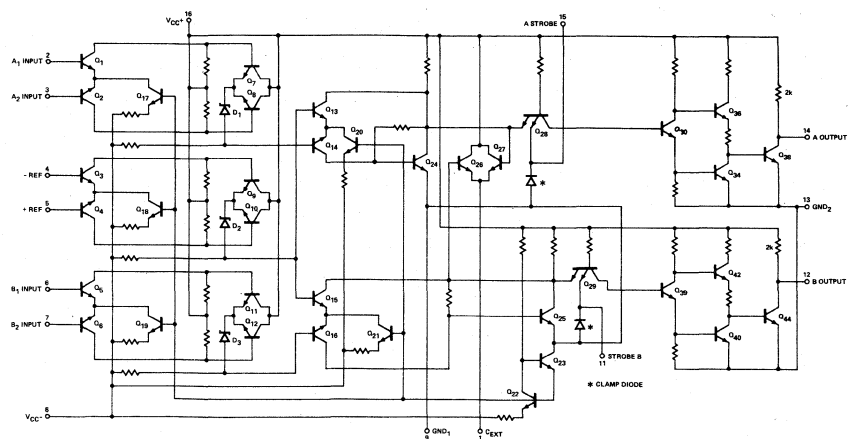
7520/21



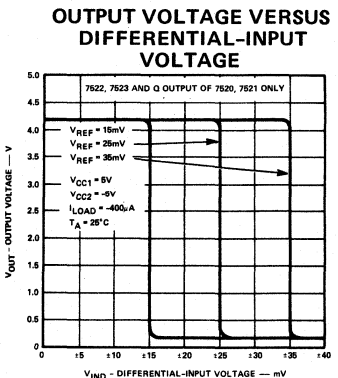
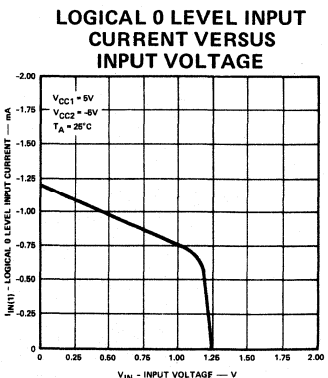
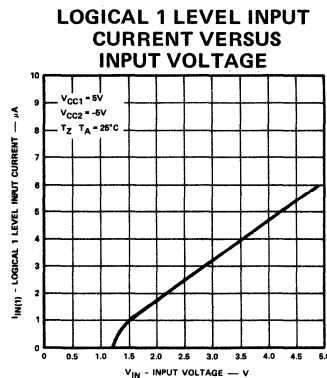
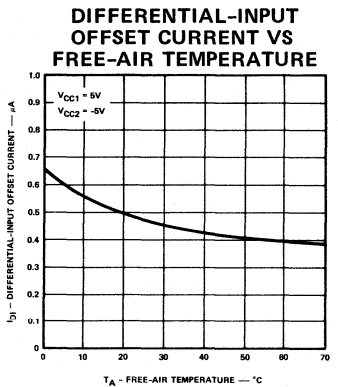
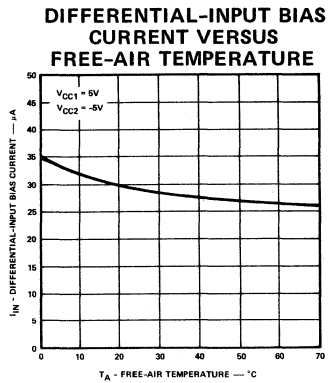
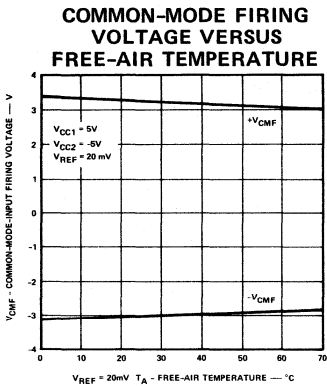
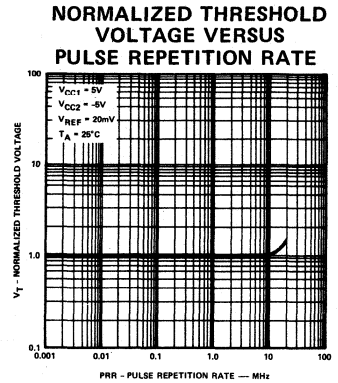
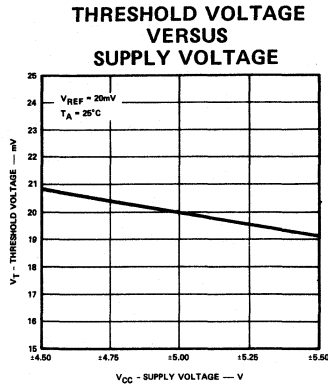
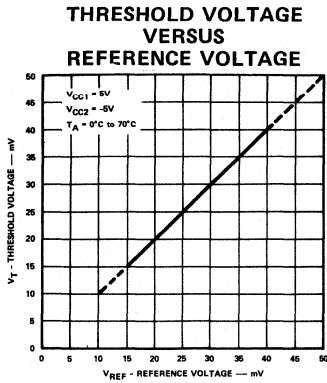
7522/23



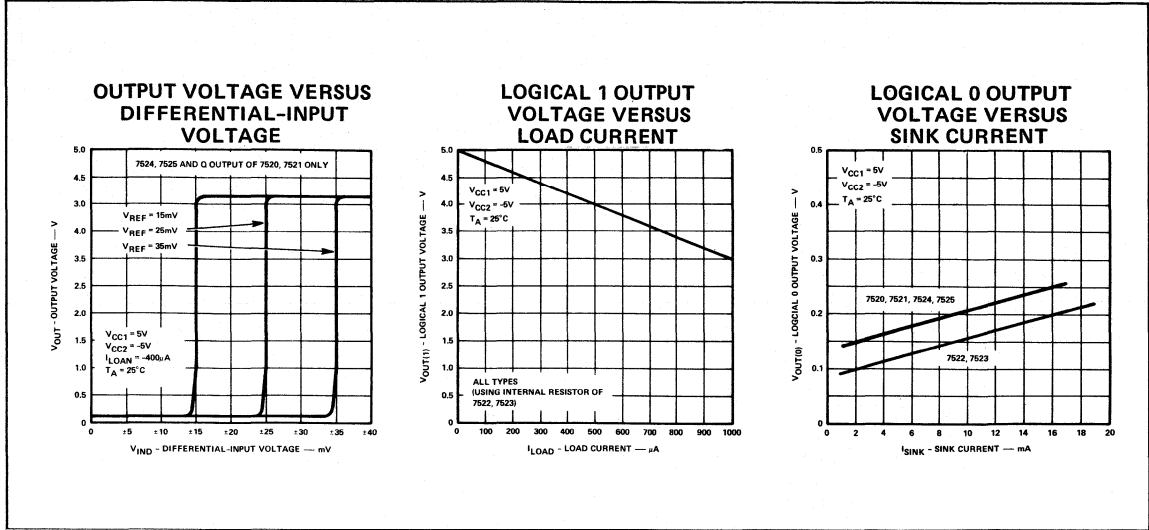
7524/25



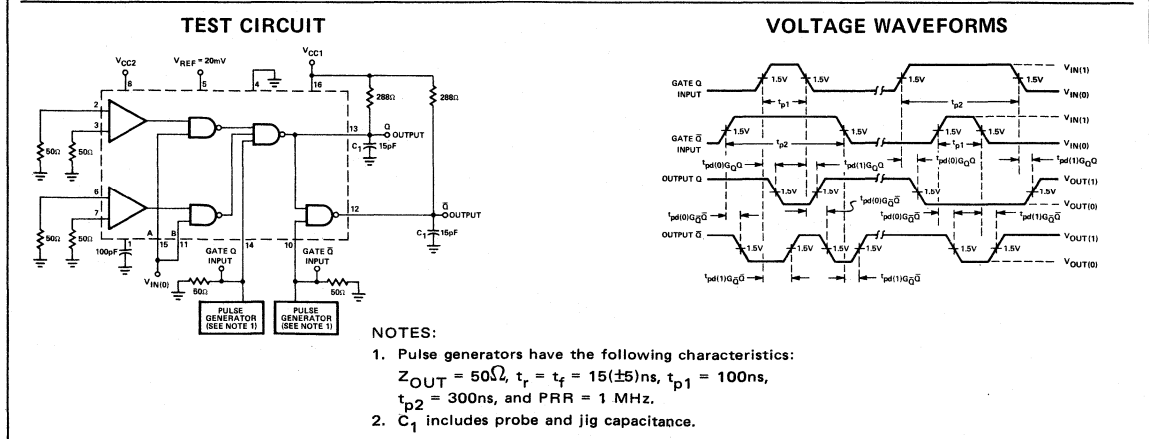
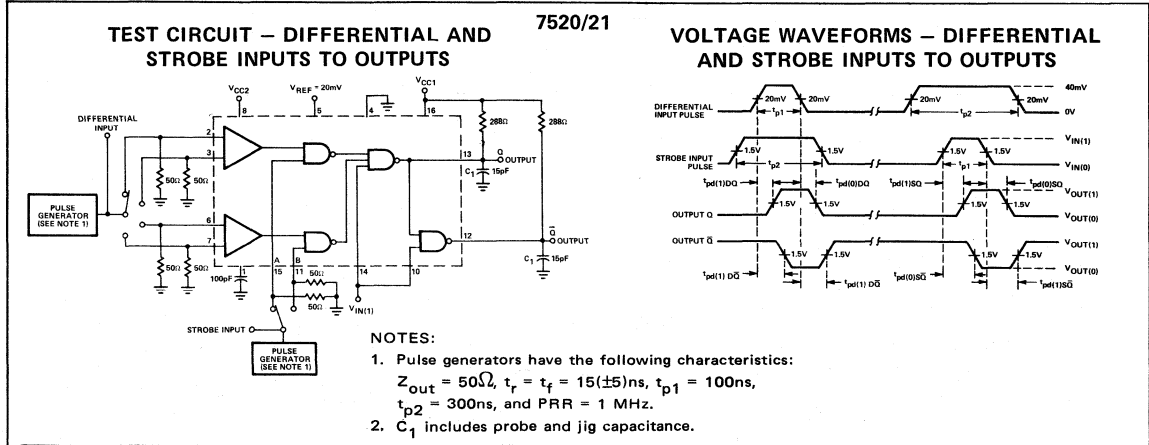
TYPICAL CHARACTERISTIC CURVES



TYPICAL CHARACTERISTIC CURVES (Cont'd.)



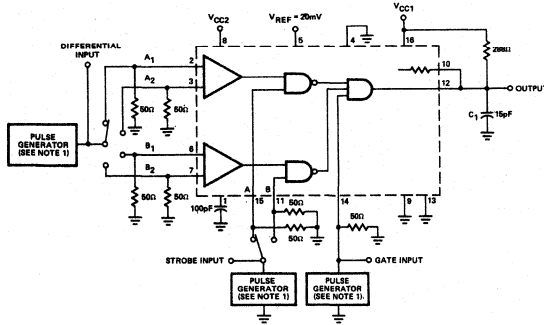
SWITCHING CHARACTERISTICS (Propagation Delay Times)



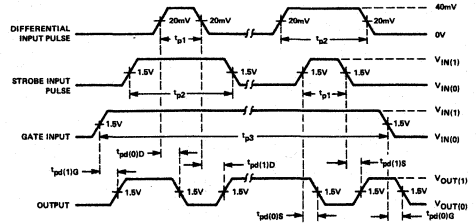
SWITCHING CHARACTERISTICS (Propagation Delay Times)(Cont'd)

7522/23

TEST CIRCUIT



VOLTAGE WAVEFORMS

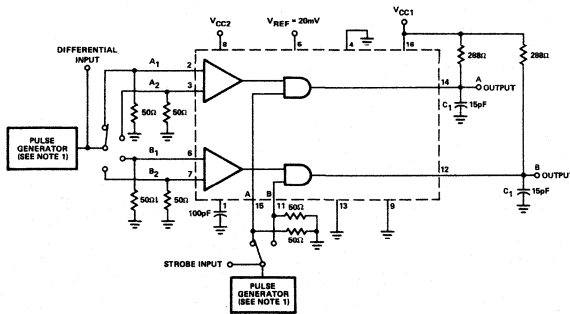


NOTES:

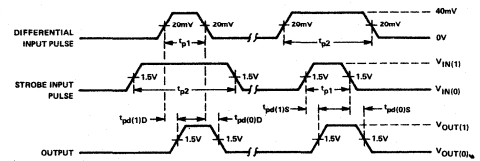
1. Pulse generators have the following characteristics:  
 $Z_{out} = 50\Omega$ ,  $t_r = t_f = 15(\pm 5)ns$ ,  $t_{p1} = 100ns$ ,  
 $t_{p2} = 300ns$ ,  $PRR = 1 MHz$ .
2. Strobe input pulse is applied to Strobe A when inputs  $A_1 - A_2$  are being tested and to Strobe B when inputs  $B_1 - B_2$  are being tested.
3.  $C_1$  includes probe and jig capacitance.

7524/25

TEST CIRCUIT



VOLTAGE WAVEFORMS



NOTES:

1. Pulse generators have the following characteristics:  
 $Z_{out} = 50\Omega$ ,  $t_r = t_f = 15(\pm 5)ns$ ,  $t_{p1} = 100ns$ ,  
 $t_{p2} = 300ns$ ,  $PRR = 1 MHz$ .
2. Strobe input pulse is applied to Strobe A when inputs  $A_1 - A_2$  are being tested and to Strobe B when inputs  $B_1 - B_2$  are being tested.
3.  $C_1$  includes probe and jig capacitance.

### DESCRIPTION

The 3207A is a Quad bipolar-to-MOS level shifter and driver used primarily as the clock driver for the 1103 and 1103A MOS RAM Memory Chips. Inputs are DTL/TTL compatible and output levels provide the high output current and voltage necessary for the 1103 and 1103A. The circuit operates from +5VDC TTL power supply and  $V_{SS}$  and  $V_{BB}$  power supplies from the 1103 and 1103A.

The 3207A features two common enable inputs per pair of devices, allowing chip enable and precharge decoding logic to be performed at the device chip.

The 3207A comes in a 16 Pin Cer DIP package.

### FEATURES

- DTL/TTL COMPATIBLE INPUTS
- 1103 AND 1103A RAM COMPATIBLE OUTPUTS
- HIGH OUTPUT SOURCE/SINK CURRENT CAPABILITY — 100mA
- HIGH SPEED — 45ns MAX.  $t_D$  WITH 200pFd LOAD
- INPUT AND OUTPUT DIODE CLAMPING TO MINIMIZE LINE REFLECTION
- HIGH INPUT BREAKDOWN VOLTAGE — 19 VOLTS

### ABSOLUTE MAXIMUM RATINGS

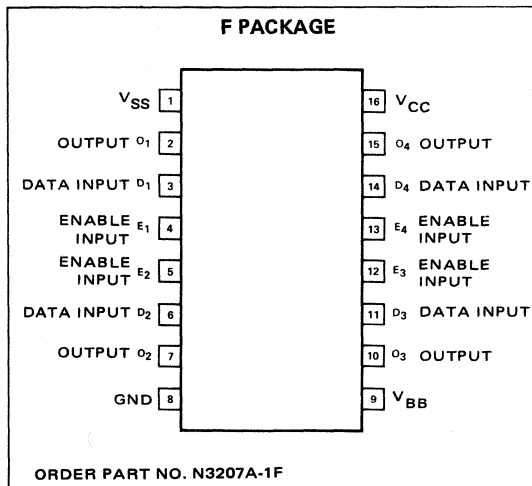
Operating Temperature Range	0° to 70°C
Storage Temperature	-65° to +150°C
Input Voltage Ranges	-0.5 to +21VDC
$V_{CC}$ Supply Voltage Range	-0.5 to +7.0VDC
Output Voltage Range (with respect to ground)	-0.5 to +25VDC
$V_{SS}$ Voltage Range (with respect to ground)	-0.5 to +25VDC
$V_{BB}$ Voltage Range	-0.5 to +25VDC

A.C. CHARACTERISTICS  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ ,  $V_{CC} = 5V \pm 5\%$ ,  $V_{BB} = V_{SS} + 3$  to  $4V$ ,  $f = 2\text{MHz}$ , 50% Duty Cycle

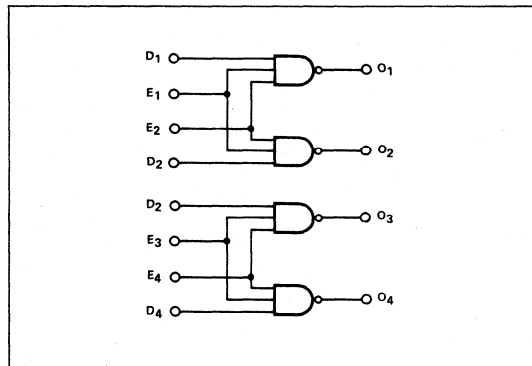
PARAMETERS	DELAY DIFFERENTIAL <sup>(1)</sup> $C_L = 200\text{ pF max.}$	$C_L = 100\text{ pF}$		$C_L = 200\text{ pF}$	
		MIN	MAX	MIN	MAX
$t_{+}$ INPUT TO OUTPUT DELAY	5	5	15	5	15
$t_{-}$ INPUT TO OUTPUT DELAY	10	5	25	5	25
$t_r$ OUTPUT RISE TIME	10	5	20	5	30
$t_f$ OUTPUT FALL TIME	10	5	20	10	30
$t_D$ DELAY + RISE OR FALL TIME	10	10	35	20	45

(1) This is defined as the maximum skew between any output in the same package, e.g., all the input to output delays for the  $t_{+}$  parameter are within a maximum of 10nsec of each other in the same package.

### PIN CONFIGURATION (Top View)



### LOGIC SYMBOL



**SIGNETICS QUAD BIPOLAR-TO-MOS CLOCK DRIVER ■ 3207A**
**D.C. CHARACTERISTICS**  $T_A = 0^\circ\text{C to } 70^\circ\text{C}$ ,  $V_{CC} = 5\text{V} \pm 5\%$ ,  $V_{SS} = 16\text{V} \pm 5\%$ ,  $V_{BB} = V_{SS} + 3.0\text{V to } 4.0\text{V}$ 

SYMBOL	PARAMETER	CONDITIONS	MIN	MAX	UNITS
$I_{FD}$	DATA INPUT LOAD CURRENT	$V_D = 0.45\text{V}$ , $V_{CC} = 5.25\text{V}$ , All Other Inputs at $5.25\text{V}$ , $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$		-0.25	mA
$I_{FE}$	ENABLE INPUT LOAD CURRENT	$V_E = 0.45\text{V}$ , $V_{CC} = 5.25\text{V}$ , All Other Inputs at $5.25\text{V}$ , $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$		-0.50	mA
$I_{RD}$	DATA INPUT LEAKAGE CURRENT	$V_D = 19\text{V}$ , $V_{CC} = 5.0\text{V}$ , All Other Inputs Grounded, $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$		20	$\mu\text{A}$
$I_{RE}$	ENABLE INPUT LEAKAGE CURRENT	$V_E = 19\text{V}$ , $V_{CC} = 5.0\text{V}$ , All Other Inputs Grounded, $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$		20	$\mu\text{A}$
$V_{OL}$	OUTPUT "LOW" VOLTAGE	$I_{OL} = 500\mu\text{A}$ , $V_{CC} = 4.75\text{V}$ $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$ All Inputs at $2.0\text{V}$		0.8 0.7 0.6	$V(0^\circ\text{C})$ $V(25^\circ\text{C})$ $V(70^\circ\text{C})$
$V_{OH}$	OUTPUT "HIGH" VOLTAGE	$I_{OH} = -500\mu\text{A}$ , $V_{CC} = 5.0\text{V}$ $V_{SS} = 16\text{V}$ , $V_{SS} = 19\text{V}$ All Inputs at $0.85\text{V}$	$V_{SS}-0.7$ $V_{SS}-0.6$ $V_{SS}-0.5$		$V(0^\circ\text{C})$ $V(25^\circ\text{C})$ $V(70^\circ\text{C})$
$V_{OH(\text{MAX.})}$		$I_{OH} = 5\text{mA}$ , $V_{CC} = 5.0\text{V}$ $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$		$V_{SS}+1.0$	V
$I_{OL}$	OUTPUT SINK CURRENT	$V_O = 4\text{V}$ , $V_{CC} = 5.0\text{V}$ , $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$ , $V_E = V_D = 2.0\text{V}$	100		mA
$I_{OH}$	OUTPUT SOURCE CURRENT	$V_O = V_{SS} - 4\text{V}$ , $V_{CC} = 5.0\text{V}$ , $V_{SS} = 16\text{V}$ $V_{BB} = 19\text{V}$ , $V_E = V_D = 0.85\text{V}$	-100		mA
$V_{IL}$	INPUT "LOW" VOLTAGE	$V_{CC} = 5.0\text{V}$ , $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$		1.0	V
$V_{IH}$	INPUT "HIGH" VOLTAGE	$V_{CC} = 5.0\text{V}$ , $V_{SS} = 16\text{V}$ , $V_{BB} = 19\text{V}$	2.0		V
$C_{IN}$	INPUT CAPACITANCE	$V_{BIAS} = 2.0\text{V}$ , $V_{CC} = 0\text{V}$	8 (Typical)		pF

**POWER SUPPLY CURRENT DRAIN:**

All Outputs "Low"

$I_{CC}$	Current from $V_{CC}$	$V_{CC} = 5.25\text{V}$ , $V_{SS} = 16.8\text{V}$		83	mA
$I_{SS}$	Current from $V_{SS}$			250	$\mu\text{A}$
$I_{BB}$	Current from $V_{BB}$	$V_{BB} = 20.8\text{V}$ All Inputs High		21	mA
$P_{TOTAL}$	Total Power Dissipation			900	mW

All Outputs "High"

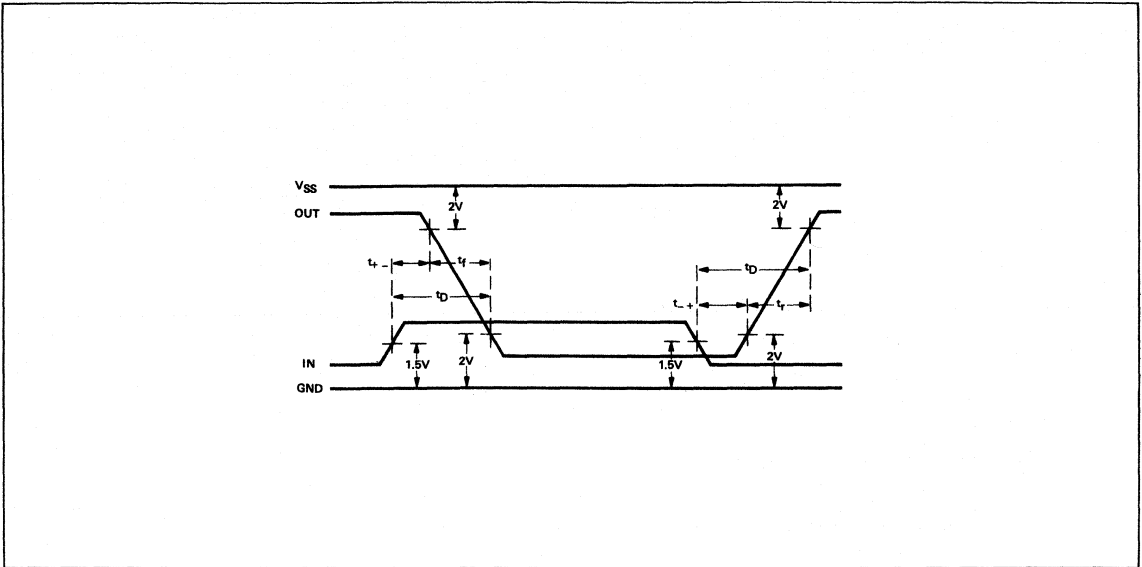
$I_{CC}$	Current from $V_{CC}$	$V_{CC} = 5.25\text{V}$ , $V_{SS} = 16.8\text{V}$		33	mA
$I_{SS}$	Current from $V_{SS}$	$V_{BB} = 20.8\text{V}$		250	$\mu\text{A}$
$I_{BB}$	Current from $V_{BB}$	All Inputs High		3	mA
$P_{TOTAL}$	Total Power Dissipation			250	mW

**STANDBY CONDITION WITH  $V_{CC} = 0\text{V}$ ,  $V_{SS} = V_{BB}$** 

$I_{CC}$	Current from $V_{CC}$	$V_{CC} = 0\text{V}$ , $V_{SS} = 16.8\text{V}$ , $V_{BB} = 16.8\text{V}$		0	mA
$I_{SS}$	Current from $V_{SS}$			250	$\mu\text{A}$
$I_{BB}$	Current from $V_{BB}$			250	$\mu\text{A}$
$P_{TOTAL}$	Total Power Dissipation			10	mW

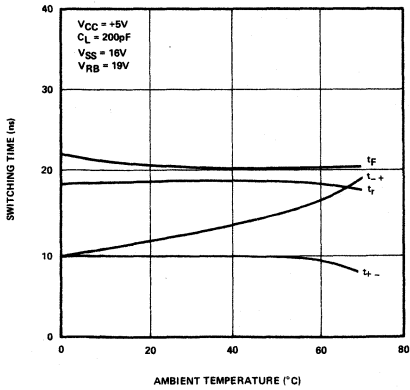


WAVEFORMS

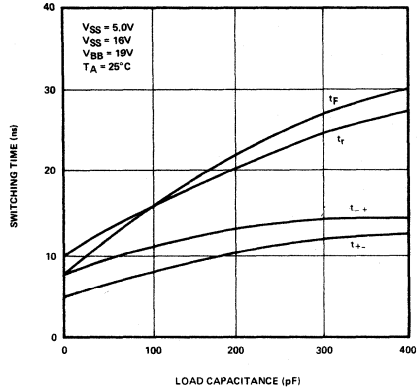


TYPICAL CHARACTERISTICS

SWITCHING TIME VS. AMBIENT TEMPERATURE



SWITCHING TIME VS. LOAD CAPACITANCE



# signetics QUAD BIPOLAR-TO-MOS CLOCK DRIVER 3207A-1

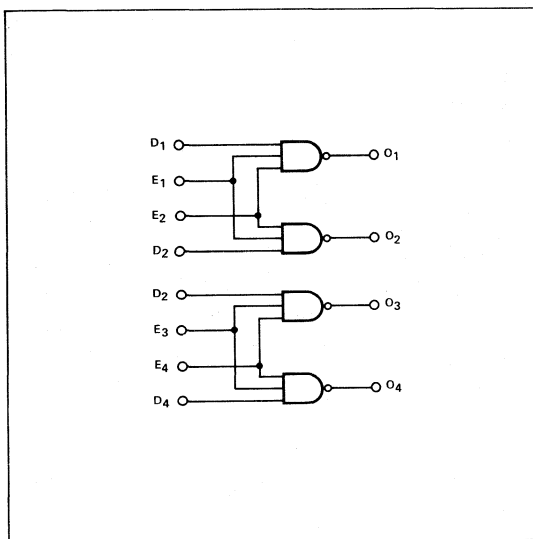
LINEAR INTEGRATED CIRCUITS

## DESCRIPTION

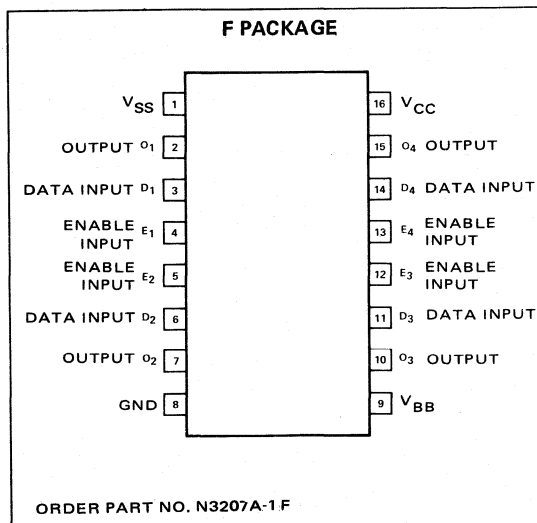
The 3207A-1 is the high voltage version of the standard 3207A and is compatible with the 1103-1 MOS RAM Memory Chip.

The 3207A-1 comes in a 16 pin Cer DIP package.

## LOGIC SYMBOL



## PIN CONFIGURATION (Top View)



## ABSOLUTE MAXIMUM RATINGS

Operating Temperature Range	0° to 70°C
Storage Temperature	-65° to +150°C
Input Voltage Ranges	-0.5 to +21VDC
V <sub>CC</sub> Supply Voltage Range	-0.5 to +7.0VDC
Output Voltage Range (with respect to ground)	-0.5 to +25VDC
V <sub>SS</sub> Voltage Range (with respect to ground)	-0.5 to +25VDC
V <sub>BB</sub> Voltage Range	-0.5 to +25VDC

**A.C. CHARACTERISTICS** T<sub>A</sub> = 0°C to 55°C, V<sub>CC</sub> = 5V ± 5%, V<sub>SS</sub> = 19V ± 5%, V<sub>BB</sub> = V<sub>SS</sub> + 3 to 4V, f = 2MHz, 50% Duty Cycle

PARAMETERS	DELAY DIFFERENTIAL <sup>(1)</sup> C <sub>L</sub> = 200 pF max.	C <sub>L</sub> = 100 pF		C <sub>L</sub> = 200 pF	
		MIN	MAX	MIN	MAX
t <sub>+ -</sub> INPUT TO OUTPUT DELAY	5	5	15	5	15
t <sub>- +</sub> INPUT TO OUTPUT DELAY	10	5	25	5	25
t <sub>r</sub> OUTPUT RISE TIME	10	5	20	5	30
t <sub>f</sub> OUTPUT FALL TIME	10	5	25	10	35
t <sub>D</sub> DELAY + RISE OR FALL TIME	10	10	35	20	45

(1) This is defined as the maximum skew between any output in the same package, e.g., all the input to output delays for the t<sub>- +</sub> parameter are within a maximum of 10nsec of each other in the same package.

**SIGNETICS QUAD BIPOLAR-TO-MOS CLOCK DRIVER ■ 3207A-1**

**D.C. CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $55^\circ\text{C}$ ,  $V_{CC} = 5\text{V} \pm 5\%$ ,  $V_{SS} = 19\text{V} \pm 5\%$ ,  $V_{BB} - V_{SS} = 3.0\text{V}$  to  $4.0\text{V}$

PARAMETER	CONDITIONS	MIN	MAX	UNITS
$I_{FD}$	DATA INPUT LOAD CURRENT $V_D = 0.45\text{V}$ , $V_{CC} = 5.25\text{V}$ , All Other Inputs at $5.25\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$		-0.25	mA
$I_{FE}$	ENABLE INPUT LOAD CURRENT $V_E = 0.45\text{V}$ , $V_{CC} = 5.25\text{V}$ , All Other Inputs at $5.25\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$		-0.50	mA
$I_{RD}$	DATA INPUT LEAKAGE CURRENT $V_D = 19\text{V}$ , $V_{CC} = 5.0\text{V}$ , All Other Inputs Grounded, $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$		20	$\mu\text{A}$
$I_{RE}$	ENABLE INPUT LEAKAGE CURRENT $V_E = 19\text{V}$ , $V_{CC} = 5.0\text{V}$ , All Other Inputs Grounded, $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$		20	$\mu\text{A}$
$V_{OL}$	OUTPUT "LOW" VOLTAGE $I_{OL} = 500\mu\text{A}$ , $V_{CC} = 4.75\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$ , All Inputs at $2.0\text{V}$		0.8 0.7 0.6	$V(0^\circ\text{C})$ $V(25^\circ\text{C})$ $V(55^\circ\text{C})$
$V_{OH}(\text{MIN.})$	OUTPUT "HIGH" VOLTAGE $I_{OH} = -500\mu\text{A}$ , $V_{CC} = 5.0\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$ , All Inputs at $0.85\text{V}$	$V_{SS}-0.7$ $V_{SS}-0.6$ $V_{SS}-0.5$		$V(0^\circ\text{C})$ $V(25^\circ\text{C})$ $V(55^\circ\text{C})$
$V_{OH}(\text{MAX.})$	$I_{OH} = 5\text{mA}$ , $V_{CC} = 5.0\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$		$V_{SS}+1.0$	V
$I_{OL}$	OUTPUT SINK CURRENT $V_O = 4\text{V}$ , $V_{CC} = 5.0\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$ , $V_E = V_D = 2.0\text{V}$	100		mA
$I_{OH}$	OUTPUT SOURCE CURRENT $V_O = V_{SS} - 4\text{V}$ , $V_{CC} = 5.0\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$ , $V_E = V_D = 0.85\text{V}$	-100		mA
$V_{IL}$	INPUT "LOW" VOLTAGE $V_{CC} = 5.0\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$		1.0	V
$V_{IH}$	INPUT "HIGH" VOLTAGE $V_{CC} = 5.0\text{V}$ , $V_{SS} = 19\text{V}$ , $V_{BB} = 23\text{V}$	2.0		V
$C_{IN}$	INPUT CAPACITANCE $V_{BIAS} = 2.0\text{V}$ , $V_{CC} = 0\text{V}$		8 (Typical)	pF

**POWER SUPPLY CURRENT DRAIN:**

All Outputs "Low"

$I_{CC}$	Current from $V_{CC}$	$V_{CC} = 5.25\text{V}$ , $V_{SS} = 20\text{V}$ , $V_{BB} = 24\text{V}$ All Inputs Open		83	mA
$I_{SS}$	Current from $V_{SS}$			250	$\mu\text{A}$
$I_{BB}$	Current from $V_{BB}$			25	mA
$P_{TOTAL}$	Total Power Dissipation			1040	mW

All Outputs "High"

$I_{CC}$	Current from $V_{CC}$	$V_{CC} = 5.25\text{V}$ , $V_{SS} = 20\text{V}$ , $V_{BB} = 24\text{V}$ All Inputs Grounded		33	mA
$I_{SS}$	Current from $V_{SS}$			250	$\mu\text{A}$
$I_{BB}$	Current from $V_{BB}$			5	mA
$P_{TOTAL}$	Total Power Dissipation			297	mW

STANDBY CONDITION WITH  $V_{CC} = 0\text{V}$ ,  $V_{SS} = V_{BB}$

$I_{CC}$	Current from $V_{CC}$	$V_{CC} = 0\text{V}$ , $V_{SS} = 20\text{V}$ , $V_{BB} = 20\text{V}$		0	mA
$I_{SS}$	Current from $V_{SS}$			500	$\mu\text{A}$
$I_{BB}$	Current from $V_{BB}$			500	$\mu\text{A}$
$P_{TOTAL}$	Total Power Dissipation			15	mW

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The 75450 is a dual peripheral driver designed for use in systems that employ TTL or DTL logic. This circuit features two standard 7400 series gates and two uncommitted, high current, high voltage, npn output driver transistors.

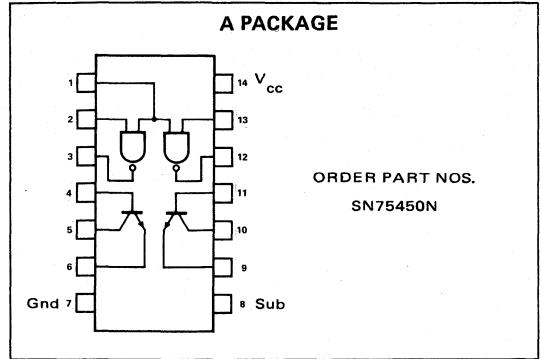
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	+7V
Input Voltage	+5.5V
Collector-Emitter Voltage	+30V
Continuous Collector Current	300mA
Continuous Total Power Dissipation	800mW

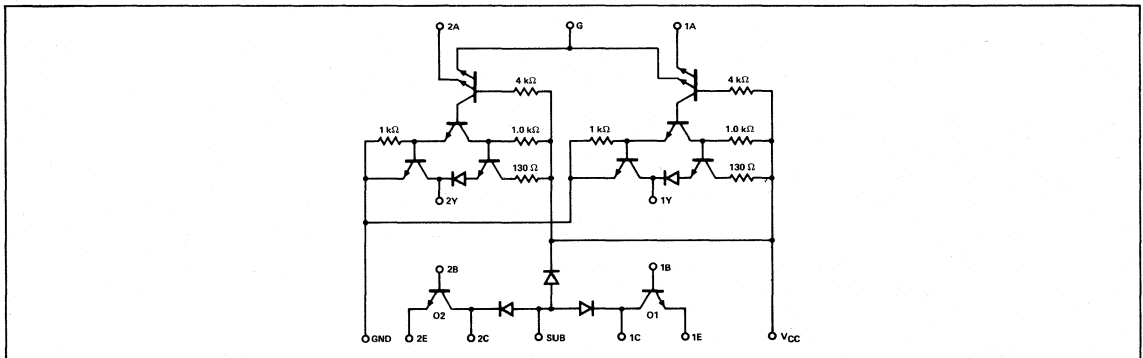
### NOTES:

- Positive Logic: Y =  $\overline{AG}$  (gate only)
- C = AG (gate and transistor)

### PIN CONFIGURATION (Top View)



### EQUIVALENT CIRCUIT



### ELECTRICAL CHARACTERISTICS - TTL GATES

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IH}$ High-Level Input Voltage		2			V
$V_{IL}$ Low-Level Input Voltage				0.8	V
$V_I$ Input Clamp Voltage	$V_{CC} = 4.75V, I_1 = -12mA$			-1.5	V
$V_{OH}$ High-Level Output Voltage	$V_{CC} = 4.75V, V_{IL} = 0.8V, I_{OM} = -400\mu A$	2.4	3.3		V
$V_{OL}$ Low-Level Output Voltage	$V_{CC} = 4.75V, V_{IH} = 2V, I_{OL} = 16mA$		0.22	0.4	V
$I_I$ Input Current at Maximum Input Voltage	Input A Input G $V_{CC} = 5.25V, V_1 = 5.5V$			1 2	mA
$I_{IH}$ High-Level Input Current	Input A Input G $V_{CC} = 5.25V, V_1 = 2.4V$			40 80	$\mu A$
$I_{IL}$ Low-Level Input Current	Input A Input G $V_{CC} = 5.25V, V_1 = 0.4V$			-1.6 -3.2	mA
$I_{OS}$ Short Circuit Output Current	$V_{CC} = 5.25V$	-18		-55	mA
$I_{CCH}$ Supply Current, High-Level Output	$V_{CC} = 5.25V, V_1 = 0$		2	4	mA
$I_{CCL}$ Supply Current, Low-Level Output	$V_{CC} = 5.25V, V_1 = 5V$		6	11	mA

## ELECTRICAL CHARACTERISTICS - OUTPUT TRANSISTORS (Cont'd)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{(BR) CBO}$ Collector-Base Breakdown Voltage	$I_C = 100\mu A, I_E = 0$	35			V
$V_{(BR) CER}$ Collector-Emitter Breakdown Voltage	$I_C = 100\mu A, R_{BE} = 500\Omega$	30			V
$V_{(BR) EBO}$ Emitter-Base Breakdown Voltage	$I_E = 100\mu A, I_C = 0$	5			V
$h_{FE}$ Static Forward Current Transfer Ratio	$V_{CE} = 3V, I_C = 100mA,$ $T_A = 25^\circ C$	25			
	$V_{CE} = 3V, I_C = 300mA,$ $T_A = 25^\circ C$	30			
	$V_{CE} = 3V, I_C = 100mA,$ $T_A = 0^\circ C$	20			
	$V_{CE} = 3V, I_C = 300mA,$ $T_A = 0^\circ C$	25			
$V_{BE}$ Base-Emitter Voltage	$I_B = 10mA, I_C = 100mA$		0.85	1	V
	$I_B = 30mA, I_C = 300mA$		1.05	1.2	V
$V_{CE (sat)}$ Collector-Emitter Saturation Voltage	$I_B = 10mA, I_C = 100mA$		0.25	0.4	V
	$I_B = 30mA, I_C = 300mA$		0.5	0.7	V

SWITCHING CHARACTERISTICS - TTL GATES ( $V_{CC} = 5V, T_A = 25^\circ C$ )

PARAMETER	TEST CONDITIONS	75450			UNIT
		MIN	TYP	MAX	
<b>TTL GATES</b>					
$t_{PLH}$ Propagation Delay Time Low-to-High-Level Output	$C_L = 15pF, R_L = 400\Omega$		12	22	ns
$t_{PHL}$ Propagation Delay Time, High-to-High-Level Output			8	15	ns
<b>OUTPUT TRANSISTORS</b>					
$t_D$ Delay Time	$I_C = 200mA, I_{B(1)} = 20mA$		8	15	ns
$t_r$ Rise Time	$I_{B(2)} = -40mA,$		12	20	ns
$t_s$ Storage Time	$V_{BE(off)} = -1V$		7	15	ns
$t_f$ Fall Time	$C_L = 15pF, R_L = 50$		6	15	ns
<b>GATES AND TRANSISTORS COMBINED</b>					
$t_{PLH}$ Propagation Delay Time, Low-to-High-Level Output			17		ns
$t_{PHL}$ Propagation Delay Time, High-to-Low-Level Output	$I_C = 200mA, C_L = 15pF,$ $R_L = 50$		16		ns
$t_{TLH}$ Transition Time, Low-to-High-Level Output			7		ns
$t_{THL}$ Transition Time, High-to-Low-Level Output			9		ns

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The SN75451 dual peripheral driver is a versatile device designed for use in systems that employ TTL or DTL logic. This circuit contains dual AND drivers (positive logic) with the gate outputs internally connected to the npn output transistors.

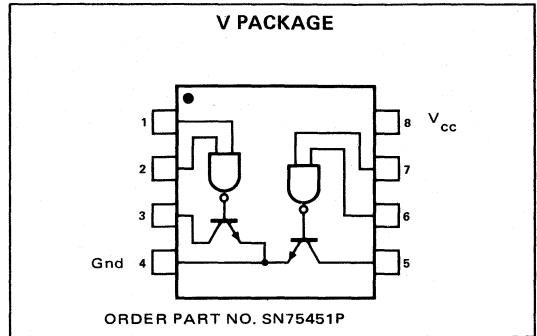
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage ( $V_{CC}$ )	+7V
Input Voltage	+5.5V
Output Voltage	+30V
Continuous Output Current	300mA
Continuous Power Dissipation	800mW
Positive Logic	Y = AB

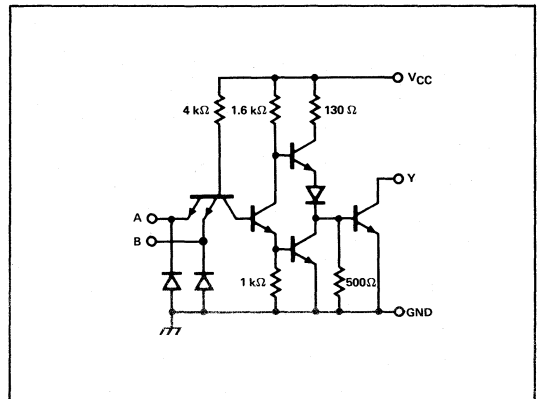
### TRUTH TABLE

A	B	Y
L	L	L (on state)
L	H	L (on state)
H	L	L (on state)
H	H	H (off state)

### PIN CONFIGURATION (Top View)



### EQUIVALENT CIRCUIT (Each Driver)



### ELECTRICAL CHARACTERISTICS

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IH}$ High-Level Input Voltage		2			V
$V_{IL}$ Low-Level Input Voltage				0.8	V
$V_I$ Input Clamp Voltage	$V_{CC} = 4.75V, I_I = -12mA$			-1.5	V
$I_{OH}$ High-Level Output Current	$V_{CC} = 4.75V, V_{IH} = 2V$ $V_{OH} = 30V$			100	$\mu A$
$V_{OL}$ Low-Level Output Voltage	$V_{CC} = 4.75V, V_{IL} = 0.8V$ $I_{OL} = 100mA$		0.25	0.4	V
	$V_{CC} = 4.75V, V_{IL} = 0.8V,$ $I_{OL} = 300mA$		0.5	0.7	V
$I_I$ Input Current at Maximum Input Voltage	$V_{CC} = 5.25V, V_I = 5.5V$			1	mA
$I_{IH}$ High-Level Input Current	$V_{CC} = 5.25V, V_I = 2.4V$			40	$\mu A$
$I_{IL}$ Low-Level Input Current	$V_{CC} = 5.25V, V_I = 0.4V$		-1	-1.6	mA
$I_{CCH}$ Supply Current, High-Level Output	$V_{CC} = 5.25V, V_I = 5V$		7	11	mA
$I_{CCL}$ Supply Current, Low-Level Output	$V_{CC} = 5.25V, V_T = 0$		52	65	mA

SWITCHING CHARACTERISTICS ( $V_{CC} = 5V$ ,  $T_A = 25^{\circ}C$ )

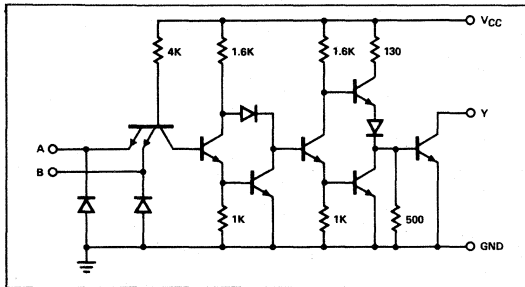
PARAMETER	TEST CONDITIONS	75451			UNITS
		MIN	TYP	MAX	
$t_{PLH}$ Propagation Delay Time Low-to-High-Level Output	$I_O \approx 200mA, C_L = 15pF$  $R_L = 50\Omega$		20	25	ns
$t_{PHL}$ Propagation Delay Time High-to-Low Level Output			20	30	ns
$t_{TLH}$ Transition Time, Low-to- High-Level Output			10		ns
$t_{THL}$ Transition Time, High-to- Low-Level Output			10		ns

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The SN75452 dual peripheral driver is a versatile device designed for use in systems that employ TTL and DTL logic. These circuits are dual NAND drivers (positive logic) with the gate outputs internally connected to the NPN output transistors.

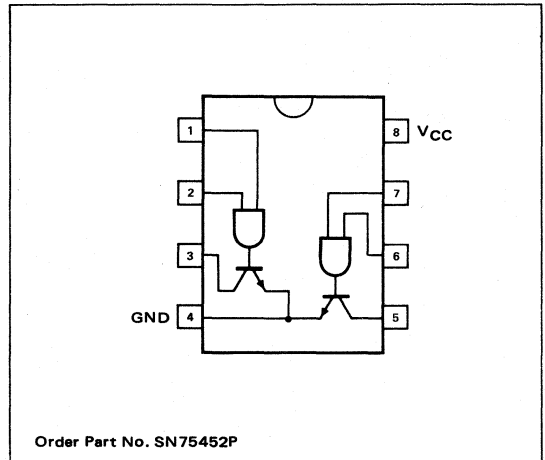
### EQUIVALENT CIRCUIT (Each Driver)



### TRUTH TABLE

A	B	Y
L	L	H (off state)
L	H	H (off state)
H	L	H (off state)
H	H	L (on state)

### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS

Supply Voltage ( $V_{CC}$ )	+7V
Input Voltage	+5.5V
Output Voltage	+30V
Continuous Output Current	300mA
Continuous Power Dissipation	800mW
Positive Logic	$Y = \overline{AB}$

ELECTRICAL CHARACTERISTICS  $V_{CC} = 5.0V \pm 5\%$ ,  $T_A = 0^\circ C$  to  $70^\circ C$ , unless otherwise noted

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IH}$	Input HIGH Voltage		2			V
$V_{IL}$	Input LOW Voltage				0.8	V
$V_{CD}$	Input Clamp Diode Voltage	$V_{CC} = 4.75V$ , $I_I = 12mA$			-1.5	V
$I_{OH}$	Output HIGH Current	$V_{CC} = 4.75V$ , $V_{OH} = 30V$ , $V_{IL} = 0.8V$			100	$\mu A$
$V_{OL}$	Output LOW Voltage	$V_{CC} = 4.75V$ , $V_{IH} = 2V$ , $I_{OL} = 100mA$		0.25	0.4	V
		$V_{CC} = 4.75V$ , $V_{IH} = 2V$ , $I_{OL} = 300mA$		0.5	0.7	
$I_I$	Input Current at Maximum Input Voltage	$V_{CC} = 5.25V$ , $V_I = 5.5V$			1.0	mA
$I_{IH}$	Input HIGH Current	$V_{CC} = 5.25V$ , $V_I = 2.4V$			40	$\mu A$
$I_{IL}$	Input LOW Current	$V_{CC} = 5.25V$ , $V_I = 0.4V$		-1.0	-1.0	mA
$I_{CCH}$	Supply Current, Output HIGH	$V_{CC} = 5.25V$ , $V_I = 0V$		11	14	mA
$I_{CCL}$	Supply Current, Output LOW	$V_{CC} = 5.25V$ , $V_I = 5V$		56	71	mA



SWITCHING CHARACTERISTICS  $V_{CC} = 5V, T_A = 25^\circ C$

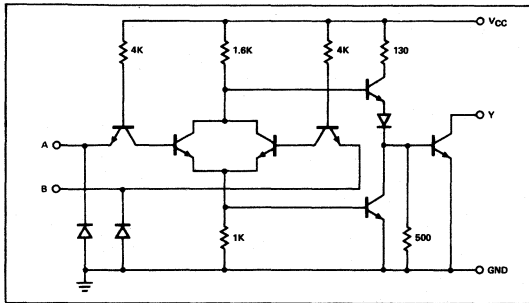
SYMBOL	PARAMETER	TEST FIGURE	CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation Delay Time, Output LOW to HIGH	14	$I_O \approx 200mA, C_L = 15pf,$ $R_L = 50\Omega$		20	25	ns
$t_{PHL}$	Propagation Delay Time, Output HIGH to LOW				20	30	ns
$t_{TLH}$	Transition Time, Output LOW to HIGH				10		ns
$t_{THL}$	Transition Time, Output HIGH to LOW				10		ns

## LINEAR INTEGRATED CIRCUITS

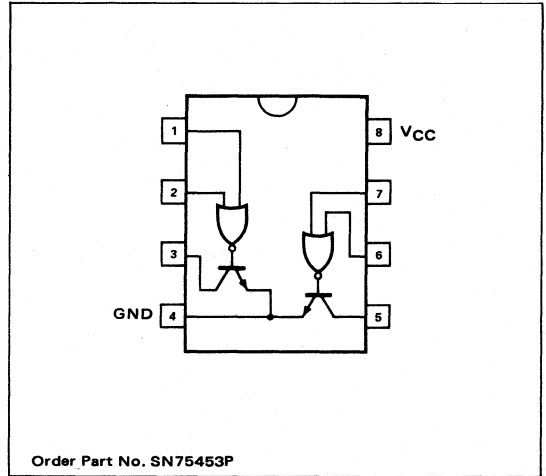
### DESCRIPTION

The SN75453 dual peripheral driver is a versatile device designed for use in systems that employ TTL or DTL logic. These circuits are dual OR drivers (positive logic) with the gate outputs internally connected to the NPN output transistors.

### EQUIVALENT CIRCUIT (Each Driver)



### PIN CONFIGURATION (Top View)



### TRUTH TABLE

A	B	Y
L	L	L (on state)
L	H	H (off state)
H	L	H (off state)
H	H	H (off state)

### ABSOLUTE MAXIMUM RATINGS

Supply Voltage ( $V_{CC}$ )	+7V
Input Voltage	+5.5V
Output Voltage	+30V
Continuous Output Current	300mA
Continuous Power Dissipation	800mW
Positive Logic	Y = AB

### ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
$V_{IH}$	Input HIGH Voltage		2			V
$V_{IL}$	Input LOW Voltage				0.8	V
$V_{CD}$	Input Clamp Diode Voltage	$V_{CC} = 4.75V, I_I = -12mA$			-1.5	V
$I_{OH}$	Output HIGH Current	$V_{CC} = 4.75V, V_{OH} = 30V$ $V_{IH} = 2V$			100	$\mu A$
$V_{OL}$	Output LOW Voltage	$V_{CC} = 4.75V, V_{IL} = 0.8V,$ $I_{OL} = 100mA$		0.25	0.4	V
		$V_{CC} = 4.75V, V_{IL} = 0.8V,$ $I_{OL} = 300mA$		0.5	0.7	
$I_I$	Input Current at Maximum Input Voltage	$V_{CC} = 5.25V, V_I = 5.5V$			1.0	mA
$I_{IH}$	Input HIGH Current	$V_{CC} = 5.25V, V_I = 2.4V$			40	$\mu A$
$I_{IL}$	Input LOW Current	$V_{CC} = 5.25V, V_I = 0.4V$		-1.0	-1.6	mA
$I_{CCH}$	Supply Current, Output HIGH	$V_{CC} = 5.25V, V_I = 5V$		8.0	11	mA
$I_{CCL}$	Supply Current, Output LOW	$V_{CC} = 5.25V, V_I = 0V$		54	68	mA

SWITCHING CHARACTERISTICS  $V_{CC} = 5V, T_A = 25^\circ C$ 

SYMBOL	PARAMETER	TEST FIGURE	CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation Delay Time, Output LOW to HIGH	14	$I_O \approx 200mA, C_L = 15pf,$ $R_L = 50\Omega$		20	25	ns
$t_{PHL}$	Propagation Delay Time, Output HIGH to LOW				20	30	ns
$t_{TLH}$	Transition Time, Output LOW to HIGH				10		ns
$t_{THL}$	Transition Time, Output HIGH to LOW				10		ns

### DESCRIPTION

The SN75454 dual peripheral driver is a versatile device designed for use in systems that employ TTL or DTL logic. The circuits are dual NOR drivers (positive logic) with the gate outputs internally connected to the npn output transistors.

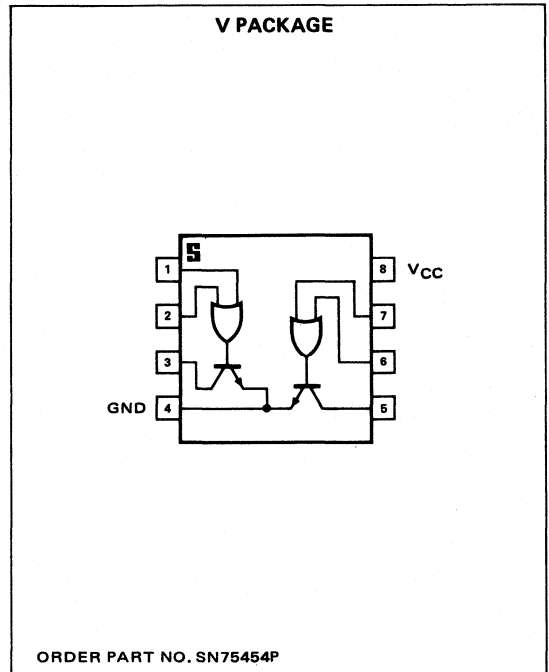
### ABSOLUTE MAXIMUM RATINGS

Supply Voltage (V <sub>CC</sub> )	+7V
Input Voltage	+5.5V
Output Voltage	+30V
Continuous Output Current	300mA
Continuous Power Dissipation	800mW
Positive Logic	$Y = \overline{A+B}$

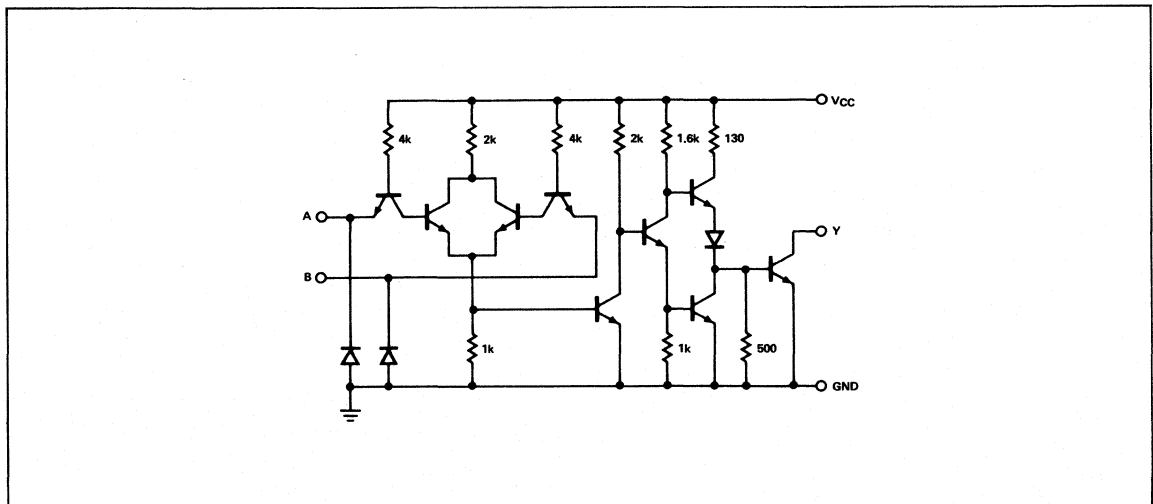
### TRUTH TABLE

A	B	Y
L	L	H (off state)
L	H	L (on state)
H	L	L (on state)
H	H	L (on state)

### PIN CONFIGURATION (Top View)



### EQUIVALENT CIRCUIT (Each Driver)



**ELECTRICAL CHARACTERISTICS**  $V_{CC} = 5.0V \pm 5\%$ ,  $T_A = 0^\circ C$  to  $70^\circ C$ , unless otherwise noted.

SYMBOL	PARAMETER	TEST FIGURE	CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IH}$	Input HIGH Voltage	7		2			V
$V_{IL}$	Input LOW Voltage	7				0.8	V
$V_{CD}$	Input Clamp Diode Voltage	8	$V_{CC} = 4.75V$ , $I_I = -12mA$			-1.5	V
$I_{OH}$	Output HIGH Voltage	7	$V_{CC} = 4.75V$ , $V_{OH} = 30V$ , $V_{IL} = 0.8V$			100	$\mu A$
$V_{OL}$	Output LOW Voltage	7	$V_{CC} = 4.75V$ , $V_{IH} = 2V$ , $I_{OL} = 100mA$		0.25	0.4	V
			$V_{CC} = 4.75V$ , $V_{IH} = 2V$ , $I_{OL} = 300mA$		0.5	0.7	
$I_I$	Input Current at Maximum Input Voltage	9	$V_{CC} = 5.25V$ , $V_I = 5.5V$			1.0	mA
$I_{IH}$	Input HIGH Current	9	$V_{CC} = 5.25V$ , $V_I = 2.4V$			40	$\mu A$
$I_{IL}$	Input LOW Current	8	$V_{CC} = 5.25V$ , $V_I = 0.4V$		-1.0	-1.6	mA
$I_{CCH}$	Supply Current, Output HIGH	11	$V_{CC} = 5.25V$ , $V_I = 0V$		13	17	mA
$I_{CCL}$	Supply Current, Output LOW		$V_{CC} = 5.25V$ , $V_I = 5V$		61	79	mA

**AC CHARACTERISTICS**  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$ 

SYMBOL	PARAMETER	TEST FIGURE	CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	Propagation Delay Time, Output LOW to HIGH				50		ns
$t_{PHL}$	Propagation Delay Time, Output HIGH to LOW	14	$I_O \approx 200mA$ , $C_L = 15pF$ , $R_L = 50\Omega$		25		ns
$t_{TLH}$	Transition Time, Output LOW to HIGH				10		ns
$t_{THL}$	Transition Time, Output HIGH to LOW				12		ns

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

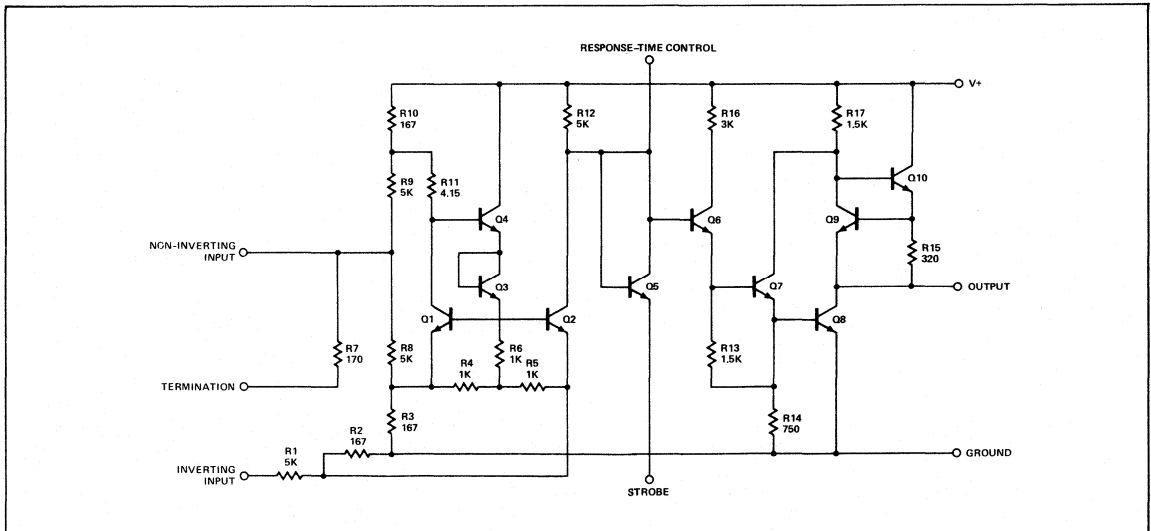
The DM7820, specified from  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ , and the DM8820, specified from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ , are digital line receivers with two completely independent units fabricated on a single silicon chip. Intended for use with digital systems connected by twisted pair lines, they have a differential input designed to reject large common mode signals while responding to small differential signals. The output is directly compatible with RTL, DTL or TTL integrated circuits.

The response time can be controlled with an external capacitor to eliminate noise spikes, and the output state is determined for open inputs. Termination resistors for the twisted pair line are also included in the circuit. Both the DM7820 and the DM8820 are specified, worst case, over their full operating temperature range, for  $\pm 10$ -percent supply voltage variations and over the entire input voltage range.

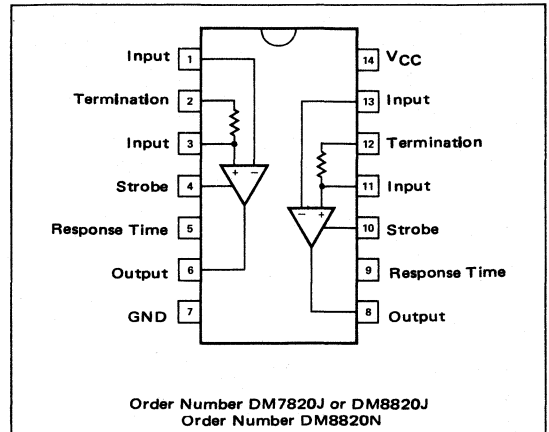
### FEATURES

- OPERATION FROM A SINGLE +5V LOGIC SUPPLY
- INPUT VOLTAGE RANGE OF  $\pm 15\text{V}$
- INDEPENDENT CHANNEL STROBING
- HIGH INPUT RESISTANCE
- FANOUT OF TWO WITH DTL OR TTL
- OUTPUT CAN BE WIRE OR'ED

### CIRCUIT SCHEMATIC



### PIN CONFIGURATION (Top View)



### ABSOLUTE MAXIMUM RATINGS

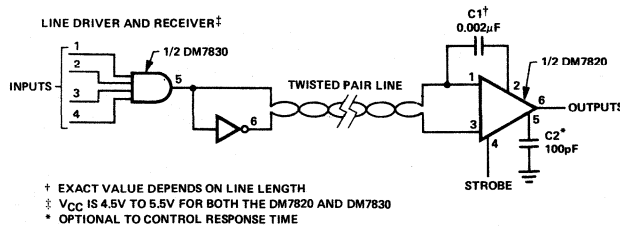
Supply Voltage	8.0V
Input Voltage	$\pm 20\text{V}$
Differential Input Voltage	$\pm 20\text{V}$
Strobe Voltage	8.0V
Output Sink Current	25mA
Power Dissipation	600mW
Operating Temperature Range (DM7820)	$-55^{\circ}\text{C}$ to $125^{\circ}\text{C}$
Operating Temperature Range (DM8820)	$0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Lead Temperature (Soldering, 10 sec)	$300^{\circ}\text{C}$

ELECTRICAL CHARACTERISTICS (Notes 1 and 2)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Threshold Voltage	$V_{IN} = 0$	-0.5	0	0.5	V
	$-15V \leq V_{IN} \leq 15V$	-1.0	0	1.0	V
High Output Level	$I_{OUT} \leq 0.2mA$	2.5		5.5	V
Low Output Level	$I_{SINK} \leq 3.5mA$	0		0.4	V
Inverting Input Resistance		3.6	5.0		k $\Omega$
Non-inverting Input Resistance		1.8	2.5		k $\Omega$
Line Termination Resistance	$T_A = 25^\circ C$	120	170	250	$\Omega$
Response Time	$C_{DELAY} = 0$		40		ns
	$C_{DELAY} = 100pF$		150		ns
Strobe Current	$V_{STROBE} = 0.4V$		1.0	1.4	mA
	$V_{STROBE} = 5.5V$			-5.0	$\mu A$
Power Supply Current	$V_{IN} = 15V$		3.2	6.0	mA
	$V_{IN} = 0$		5.8	10.2	mA
	$V_{IN} = -15V$		8.3	15.0	mA
Non-inverting Input Current	$V_{IN} = 15V$		5.0	7.0	mA
	$V_{IN} = 0$	-1.6	-1.0		mA
	$V_{IN} = -15V$	-9.8	-7.0		mA
Inverting Input Current	$V_{IN} = 15V$		3.0	4.2	mA
	$V_{IN} = 0$		0	0.5	mA
	$V_{IN} = -15V$	-4.2	-3.0		mA

- NOTES
1. These specifications apply for  $4.5V \leq V_{CC} \leq 5.5V$ ,  $-15V \leq V_{CM} \leq 15V$  and  $-55^\circ C \leq T_A \leq 125^\circ C$  for the DM7820 or  $0^\circ C \leq T_A \leq 70^\circ C$  for the DM8820 unless otherwise specified: typical values given are for  $V_{CC} = 5.0V$ ,  $T_A = 25^\circ C$  and  $V_{CM} = 0$  unless stated differently.
  2. The specifications and curves given are for one side only. Therefore, the total package dissipation and supply currents will be double the values given when both receivers are operated under identical conditions.

TYPICAL APPLICATION



#### DESCRIPTION

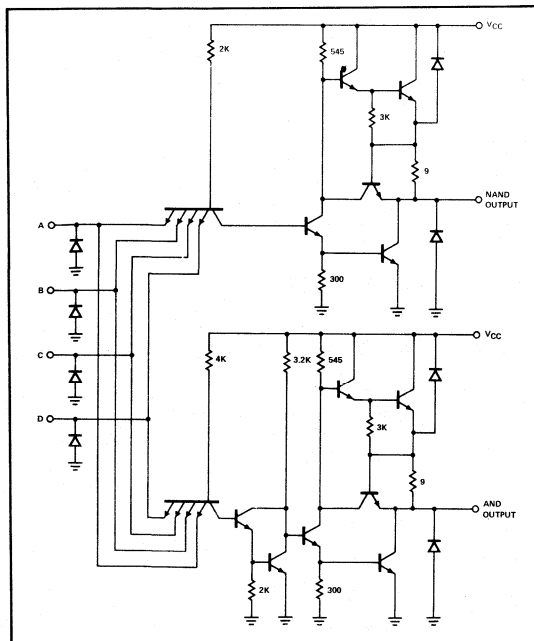
The DM7830/DM8830 is a dual differential line driver that also performs the dual four-input NAND or dual four-input AND function.

TTL (Transistor-Transistor-Logic) multiple emitter inputs allow this line driver to interface with standard TTL or DTL systems. The differential outputs are balanced and are designed to drive long lengths of coaxial cable, strip line, or twisted pair transmission lines with characteristic impedances of  $50\Omega$  to  $500\Omega$ . The differential feature of the output eliminates troublesome ground-loop errors normally associated with single-wire transmissions.

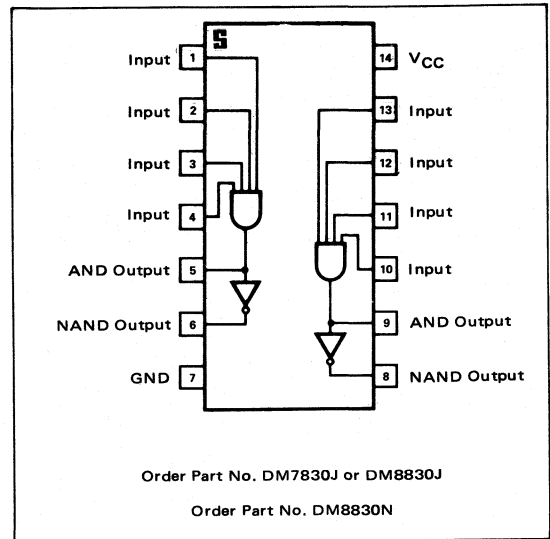
#### FEATURES

- SINGLE 5 VOLT POWER SUPPLY
- HIGH SPEED
- DIODE PROTECTED OUTPUTS FOR TERMINATION OF POSITIVE AND NEGATIVE VOLTAGE TRANSIENTS
- DIODE PROTECTED INPUTS TO PREVENT LINE RINGING
- SHORT CIRCUIT PROTECTION

#### CIRCUIT SCHEMATIC



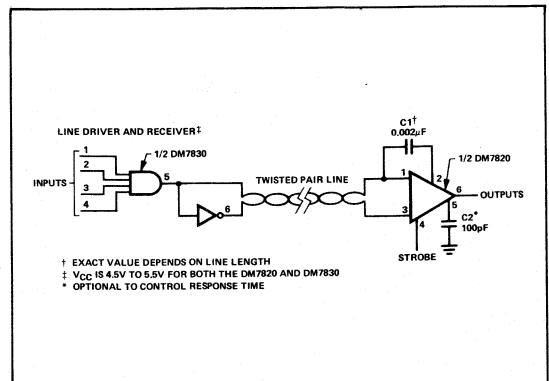
#### PIN CONFIGURATION (Top View)



#### ABSOLUTE MAXIMUM RATINGS

$V_{CC}$	7.0V
Input Voltage	5.5V
Operating Temperature	DM7830 $-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$
	DM8830 $0^{\circ}\text{C}$ to $70^{\circ}\text{C}$
Storage Temperature	$-65^{\circ}\text{C}$ to $+150^{\circ}\text{C}$
Lead Temperature (Soldering, 10 sec)	$300^{\circ}\text{C}$
Output Short Circuit Duration ( $125^{\circ}\text{C}$ )	1 second

#### TYPICAL APPLICATION



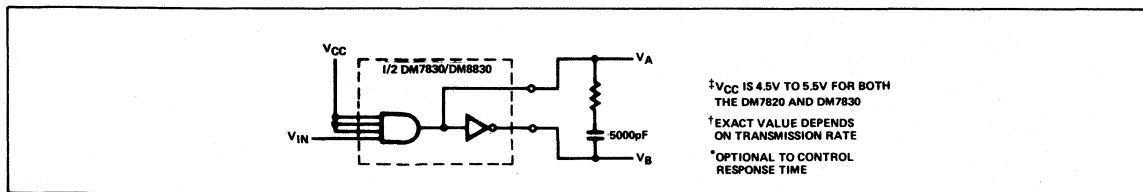


ELECTRICAL CHARACTERISTICS (Note 1)

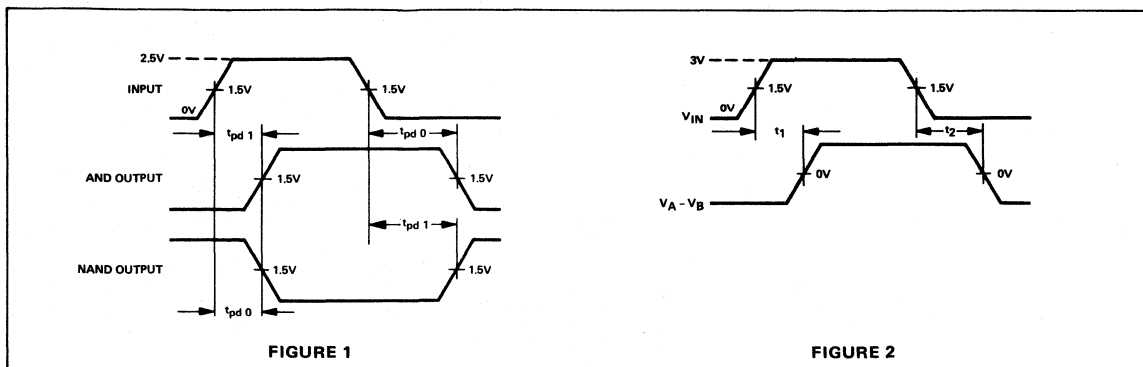
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Logical "1" Input Voltage		2.0			V
Logical "0" Input Voltage				0.8	V
Logical "1" Output Voltage	$V_{IN} = 0.8V$ $I_{OUT} = -0.8mA$	2.4			V
Logical "1" Output Voltage	$V_{IN} = 0.8V$ $I_{OUT} = -40mA$	1.8	2.9		V
Logical "0" Output Voltage	$V_{IN} = 2.0V$ $I_{OUT} = +32mA$		0.2	0.4	V
Logical "0" Output Voltage	$V_{IN} = 2.0V$ $I_{OUT} = +40mA$		0.22	0.5	V
Logical "1" Input Current	$V_{IN} = +2.4V$			120	$\mu A$
Logical "1" Input Current	$V_{IN} = 5.5V$			2	mA
Logical "0" Input Current	$V_{IN} = 0.4V$			4.8	mA
Output Short Circuit Current	$V_{CC} = 5.0V$	Note 2 -40	-100	Note 2 -120	mA
Supply Current	$V_{CC} = 5.0V$ $V_{IN} = 5.0V$ (Each Driver)		11	18	mA
Propagation Delay AND Gate	$T_A = 25^\circ C$ $V_{CC} = 5.0V$	$t_{pd 1}$	8	12	ns
		$t_{pd 0}$	11	18	ns
Propagation Delay NAND Gate	$C_L = 15pF$ See Figure 1	$t_{pd 1}$	8	12	ns
		$t_{pd 0}$	5	8	ns
Differential Delay $t_1$	Load, 100 $\Omega$ and 5000pF		12	16	ns
Differential Delay $t_2$	See Figure 2		12	16	ns

- NOTES
- Specifications apply for DM7830  $-55^\circ C \leq T_A \leq +125^\circ C$ ,  $V_{CC} = +5V \pm 10\%$ , DM8830  $0^\circ C \leq T_A \leq 70^\circ C$ ,  $V_{CC} = +5V \pm 5\%$  unless otherwise stated. Typical values given are for  $T_A = 25^\circ C$ ,  $V_{CC} = 5.0V$ .
  - Applies for  $T_A = +125^\circ C$  only.

AC TEST CIRCUIT



SWITCHING TIME WAVEFORMS



### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

The DM8880 is a High Voltage Seven-Segment Decoder/Driver designed to decode BCD and drive gas filled seven-segment display tubes.

Decoding is performed by a 16x7 read only memory. Thus, for applications desiring other fonts, or applications not using standard BCD inputs, the ROM contents can be altered via metal mask change to produce any seven-segment combination for any 16 binary input combinations.

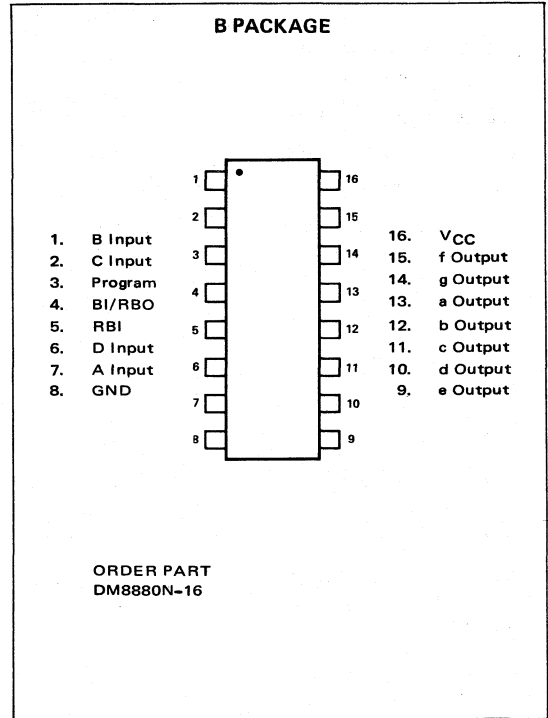
The output of the ROM is used to drive high voltage constant current sink generators. The current sinks will withstand 80V output min. The current sinks are ratioed to the B output current as required for even illumination of the segments. Output currents may be varied over a 0.2 to 1.5 mA range through use of the external current programming input.

Blanking input provides unconditional blanking of any output display, while the ripple blanking pins allow simple leading or trailing zero blanking.

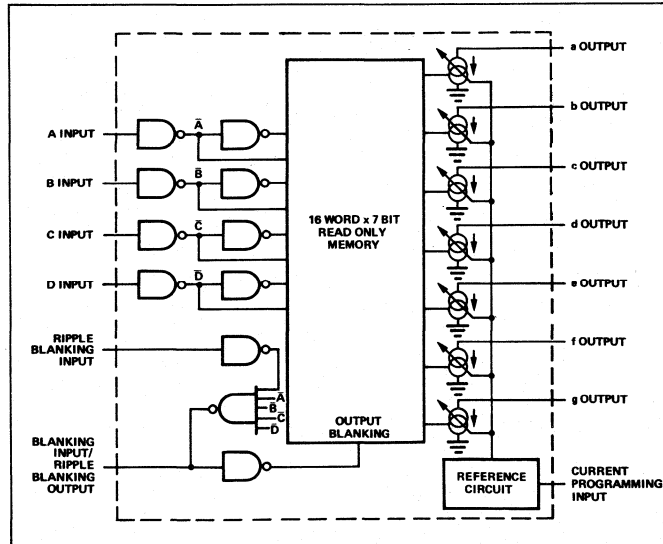
#### FEATURES

- CURRENT SOURCE OUTPUTS
- ADJUSTABLE OUTPUT CURRENT – 0.2 TO 1.5 mA
- HIGH OUTPUT BREAKDOWN VOLTAGE – 110V TYP
- SUITABLE FOR MULTIPLEX OPERATION
- BLANKING AND RIPPLE BLANKING PROVISIONS
- LOW FAN-IN AND LOW POWER

#### PIN CONFIGURATION (Top View)



#### LOGIC AND CONNECTION DIAGRAMS



#### TRUTH TABLE

SEGMENT IDENTIFICATION

DECIMAL OR FUNCTION	RBI	D	C	B	A	BI/RBO	a	b	c	d	e	f	g	DISPLAY
0	1	0	0	0	0	1	0	0	0	0	0	0	1	0
1	X	0	0	0	1	1	1	0	0	1	1	1	1	1
2	X	0	0	1	0	1	0	0	1	0	0	1	0	1
3	X	0	0	1	1	1	0	0	0	0	0	1	1	0
4	X	0	1	0	0	1	1	0	0	1	1	0	0	0
5	X	0	1	0	1	1	0	1	0	0	1	0	0	0
6	X	0	1	1	0	1	0	1	0	0	0	0	0	0
7	X	0	1	1	1	1	0	0	0	1	1	1	1	1
8	X	1	0	0	0	1	0	0	0	0	0	0	0	0
9	X	1	0	0	1	1	0	0	0	0	1	0	0	0
10	X	1	0	1	0	1	0	0	0	1	0	0	0	0
11	X	1	0	1	1	1	1	1	0	0	0	0	0	0
12	X	1	1	0	0	1	0	1	0	0	0	0	0	1
13	X	1	1	0	1	1	1	0	0	0	0	1	0	0
14	X	1	1	1	0	1	0	1	1	0	0	0	0	0
15	X	1	1	1	1	1	0	1	1	1	1	0	0	0
BI	X	X	X	X	X	X	0	1	1	1	1	1	1	1
RBI	0	0	0	0	0	0	1	1	1	1	1	1	1	1

## ABSOLUTE MAXIMUM RATINGS

VCC	7V
Input Voltage (Except B1)	6V
Input Voltage (B1)	VCC
Power Dissipation (Note 1)	600mW
Operating Temperature Range	0°C to 70°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

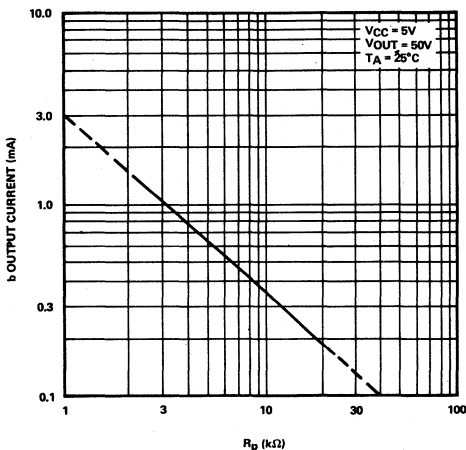
## ELECTRICAL CHARACTERISTICS (Note 1)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Logic "1" Input Voltage	VCC = 4.75V	2.0			V
Logic "0" Input Voltage	VCC = 4.75V			0.8	V
Logic "1" Output Voltage (RBO)	VCC = 4.75V, I <sub>OUT</sub> = -200μA	2.4	3.7		V
Logic "0" Output Voltage (RBO)	VCC = 4.75V, I <sub>OUT</sub> = 8mA		0.13	0.4	V
Logic "1" Input Current (Except B1)	VCC = 5.25V, V <sub>IN</sub> = 2.4V		2	15	μA
	VCC = 5.25V, V <sub>IN</sub> = 5.5V		4	400	μA
Logic "0" Input Current (Except B1)	VCC = 5.25V, V <sub>IN</sub> = 0.4V		-300	-600	μA
Logic "0" Input Current (B1)	VCC = 5.25V, V <sub>IN</sub> = 0.4V		-1.2	-2.0	mA
Power Supply Current	VCC = 5.25V, All Inputs = 0V, R <sub>p</sub> = 2.2k		27	43	mA
Input Diode Clamp Voltage	VCC = 5V, I <sub>IN</sub> = -12mA, T <sub>A</sub> = 25°C		-0.9	-1.5	V
Segment Outputs:					
Outputs a, f, g On Current Ratio	All Outputs = 50V, Output b Curr. = Ref.	0.88	0.93	0.98	
Output c On Current Ratio	All Outputs = 50V, Output b Curr. = Ref.	1.19	1.25	1.31	
Output d On Current Ratio	All Outputs = 50V, Output b Curr. = Ref.	0.95	1.00	1.05	
Output e On Current Ratio	All Outputs = 50V, Output b Curr. = Ref.	1.04	1.10	1.16	
Output b On Current	VCC = 5V, V <sub>OUT</sub> b = 50V, T <sub>A</sub> = 25°C, R <sub>p</sub> = 18.1k	0.18	0.20	0.22	mA
	VCC = 5V, V <sub>OUT</sub> b = 50V, T <sub>A</sub> = 25°C, R <sub>p</sub> = 7.03k	0.45	0.50	0.55	mA
	VCC = 5V, V <sub>OUT</sub> b = 50V, T <sub>A</sub> = 25°C, R <sub>p</sub> = 3.40k	0.90	1.00	1.10	mA
	VCC = 5V, V <sub>OUT</sub> b = 50V, T <sub>A</sub> = 25°C, R <sub>p</sub> = 2.20k	1.45	1.50	1.65	mA
Output Saturation Voltage	VCC = 4.75V, I <sub>OUT</sub> = 2mA, R <sub>p</sub> = 1k ±5%		0.8	2.5	V
Output Leakage Current	V <sub>OUT</sub> = 75V, B1 = 0V		.003	3	μA
Output Breakdown Voltage	I <sub>OUT</sub> = 250μA, B1 = 0V	80	110		V
Propagation Delays:					
BCD Input to Segment Output	VCC = 5V, T <sub>A</sub> = 25°C		0.4	10	μs
B1 to Segment Output	VCC = 5V, T <sub>A</sub> = 25°C		0.4	10	μs
RBI to Segment Output	VCC = 5V, T <sub>A</sub> = 25°C		0.7	10	μs
RBI to RBO	VCC = 5V, T <sub>A</sub> = 25°C		0.4	10	μs

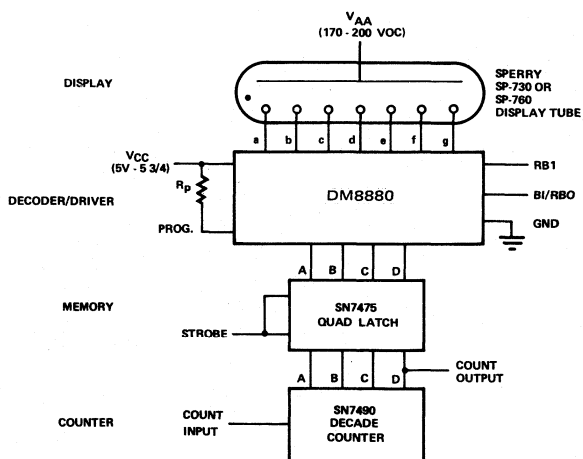
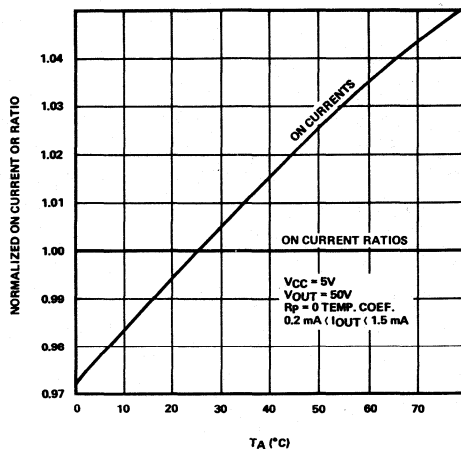
Note 1: Min/max limits apply across the guaranteed operating temperature range of 0°C to 70°C unless otherwise specified. Typical values are for VCC = 5V, T<sub>A</sub> = 25°C. Positive current is defined as current into the referenced pin.

TYPICAL APPLICATION

OUTPUT CURRENT PROGRAMMING



ON CURRENTS vs. TEMPERATURE



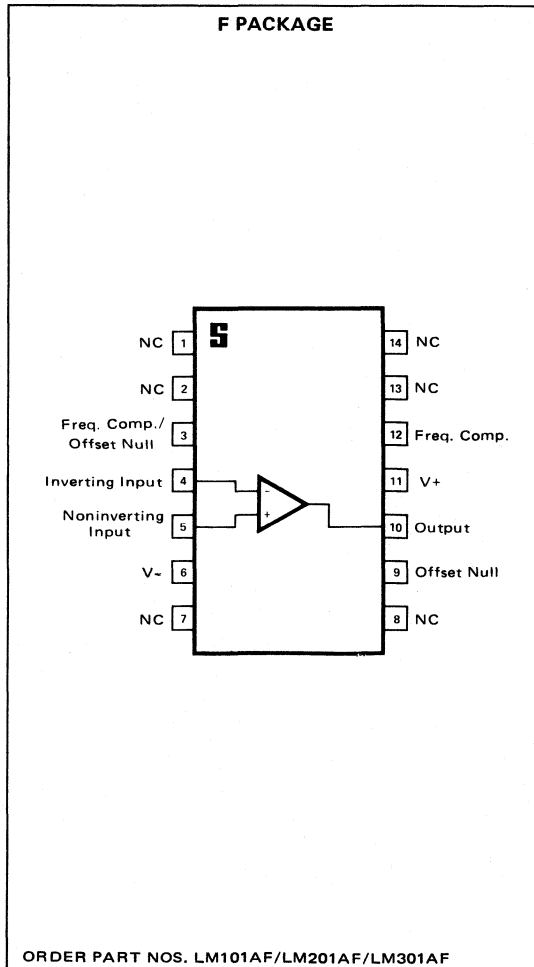
#### DESCRIPTION

The LM101A, LM201A, and LM301A are high performance operational amplifiers featuring high gain, short circuit protection, simplified compensation and excellent temperature stability.

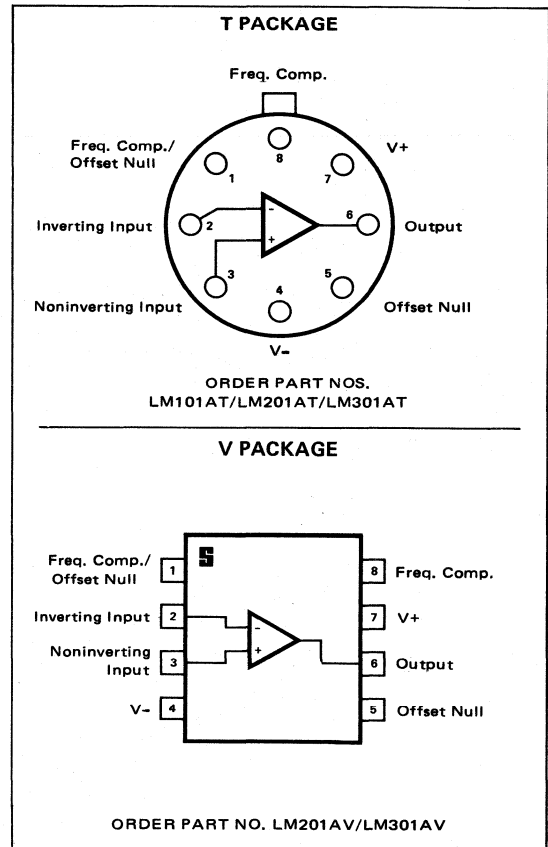
#### FEATURES

- SHORT CIRCUIT PROTECTION
- OFFSET VOLTAGE NULL CAPABILITY
- LARGE COMMON-MODE AND DIFFERENTIAL VOLTAGE RANGES
- LOW POWER CONSUMPTION
- NO LATCH UP

#### PIN CONFIGURATIONS (Top Views)



#### PIN CONFIGURATIONS (Top Views)



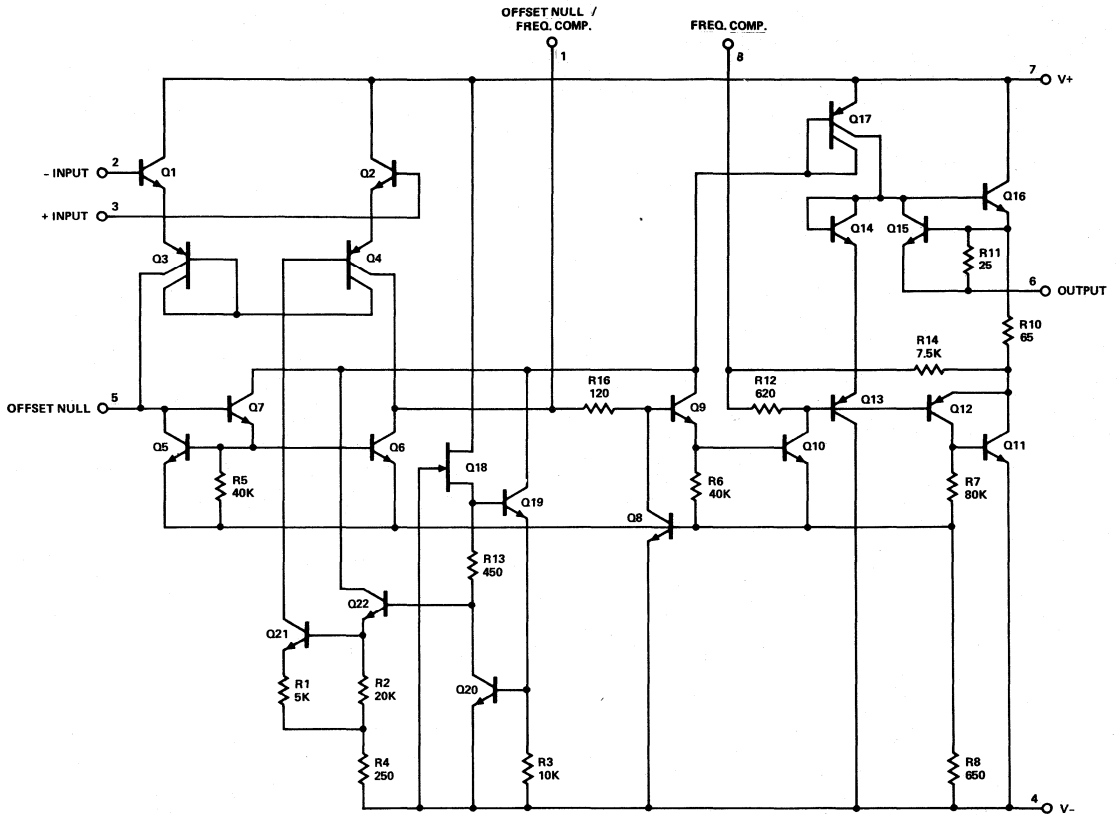
#### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	LM101A/LM201A	±22V
	LM301A	±18V
Power Dissipation (Note 1)		500mW
Differential Input Voltage		±30V
Input Voltage (Note 2)		±15V
Output Short Circuit Duration		Indefinite
Operating Temperature Range	LM101A	-55°C to 125°C
	LM201A	-25°C to 85°C
	LM301A	0°C to 70°C
Storage Temperature Range		-65°C to 150°C
Lead Temperature (Soldering, 60 sec.)		300°C

#### NOTES:

1. Absolute maximum rating holds for all packages. The maximum junction temperature is 150°C for the LM101A and 100°C for the LM201A and the LM301A. For operation at elevated temperatures, derate according to appropriate thermal resistances given under package information.
2. For supply voltages less than ±15V, the absolute maximum input voltage is equal to the supply voltage.

SCHEMATIC DIAGRAM



NOTE: Pin numbers for T Package.

**ELECTRICAL CHARACTERISTICS**

LM101A:  $-55^{\circ}\text{C} \leq T_A \leq 125^{\circ}\text{C}$

LM201A:  $-25^{\circ}\text{C} \leq T_A \leq 85^{\circ}\text{C}$   $\pm 5\text{V} \leq V_S \leq \pm 20\text{V}$  and  $C_1 = 30\text{pF}$

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	$T_A = 25^{\circ}\text{C}$ , $R_S \leq 50\text{k}\Omega$		0.7	2.0	mV
Input Offset Current	$T_A = 25^{\circ}\text{C}$		1.5	10	nA
Input Bias Current	$T_A = 25^{\circ}\text{C}$		30	75	nA
Input Resistance	$T_A = 25^{\circ}\text{C}$	1.5	4		M $\Omega$
Supply Current	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 20\text{V}$		1.8	3.0	mA
Large Signal Voltage Gain	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 15\text{V}$ $V_{OUT} = \pm 10\text{V}$ , $R_L \geq 2\text{k}\Omega$	50	160		V/mV
Input Offset Voltage	$R_S \leq 50\text{k}\Omega$			3.0	mV
Average Temperature Coefficient of Input Offset Voltage			3.0	15	$\mu\text{V}/^{\circ}\text{C}$
Input Offset Current				20	nA
Average Temperature Coefficient of Input Offset Current	$25^{\circ}\text{C} < T_A < 125^{\circ}\text{C}$ $-55^{\circ}\text{C} < T_A < 25^{\circ}\text{C}$		0.01 0.02	0.1 0.2	nA/ $^{\circ}\text{C}$ nA/ $^{\circ}\text{C}$
Input Bias Current				100	nA
Supply Current	$T_A = +125^{\circ}\text{C}$ , $V_S = \pm 20\text{V}$		1.2	2.5	mA
Large Signal Voltage Gain	$V_S = \pm 15\text{V}$ , $V_{OUT} = \pm 10\text{V}$ $R_L \geq 2\text{k}\Omega$	25			V/mV
Output Voltage Swing	$V_S = \pm 15\text{V}$ , $R_L = 10\text{k}\Omega$ $R_L = 2\text{k}\Omega$	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$		V V
Input Voltage Range	$V_S = \pm 20\text{V}$	$\pm 15$			V
Common Mode Rejection Ratio	$R_S \leq 50\text{k}\Omega$	80	96		dB
Supply Voltage Rejection Ratio	$R_S \leq 50\text{k}\Omega$	80	96		dB

**LM301A**

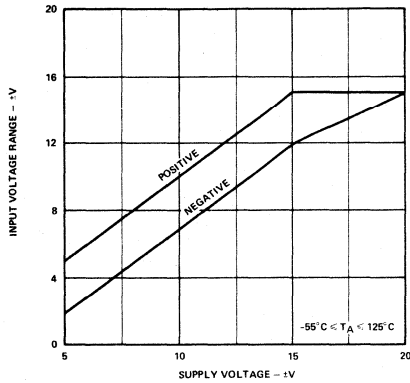
**ELECTRICAL CHARACTERISTICS**  $0^{\circ}\text{C} \leq T_A < 70^{\circ}\text{C}$ ,  $\pm 5\text{V} \leq V_S \leq \pm 15\text{V}$  and  $C_1 = 30\text{pF}$

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
Input Offset Voltage	$T_A = 25^{\circ}\text{C}$ , $R_S \leq 50\text{k}\Omega$		2.0	7.5	mV
Input Offset Current	$T_A = 25^{\circ}\text{C}$		3	50	nA
Input Bias Current	$T_A = 25^{\circ}\text{C}$		70	250	nA
Input Resistance	$T_A = 25^{\circ}\text{C}$	0.5	2		M $\Omega$
Supply Current	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 15\text{V}$		1.8	3.0	mA
Large Signal Voltage Gain	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 15\text{V}$ $V_{OUT} = \pm 10\text{V}$ ; $R_L \geq 2\text{k}\Omega$	25	160		V/mV
Input Offset Voltage	$R_S \leq 50\text{k}\Omega$			10	mV
Average Temperature Coefficient of Input Offset Voltage			6.0	30	$\mu\text{V}/^{\circ}\text{C}$
Input Offset Current				70	nA
Average Temperature Coefficient of Input Offset Current	$25^{\circ}\text{C} < T_A < 70^{\circ}\text{C}$ $0^{\circ}\text{C} < T_A < 25^{\circ}\text{C}$		0.01 0.02	0.3 0.6	nA/ $^{\circ}\text{C}$ nA/ $^{\circ}\text{C}$
Input Bias Current				300	nA
Large Signal Voltage Gain	$V_S = \pm 15\text{V}$ , $V_{OUT} = \pm 10\text{V}$ $R_L \geq 2\text{k}\Omega$	15			V/mV
Output Voltage Swing	$V_S = \pm 15\text{V}$ , $R_L = 10\text{k}\Omega$ $R_L = 2\text{k}\Omega$	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$		V V
Input Voltage Range	$V_S = \pm 15\text{V}$	$\pm 12$			V
Common Mode Rejection Ratio	$R_S \leq 50\text{k}\Omega$	70	90		dB
Supply Voltage Rejection Ratio	$R_S \leq 50\text{k}\Omega$	70	96		dB

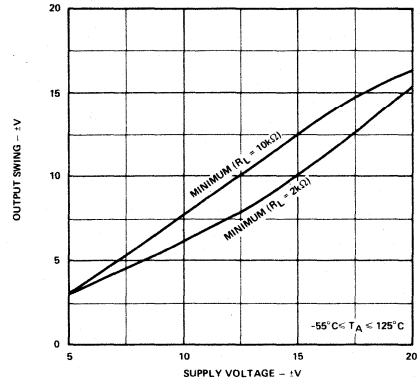
GUARANTEED PERFORMANCE CHARACTERISTICS

LM101A/LM201A

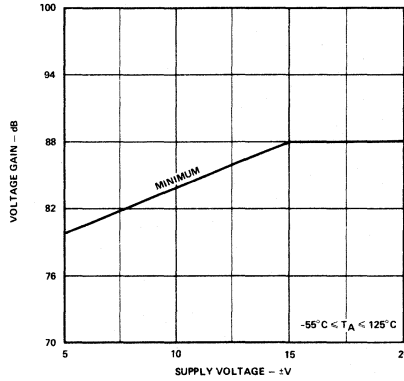
INPUT VOLTAGE RANGE



OUTPUT SWING



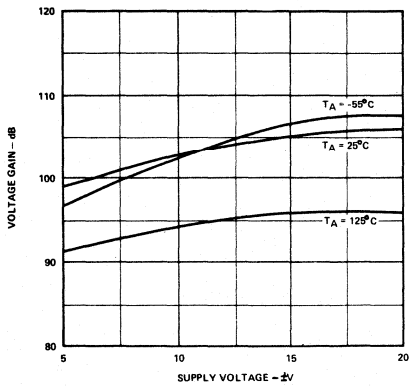
VOLTAGE GAIN



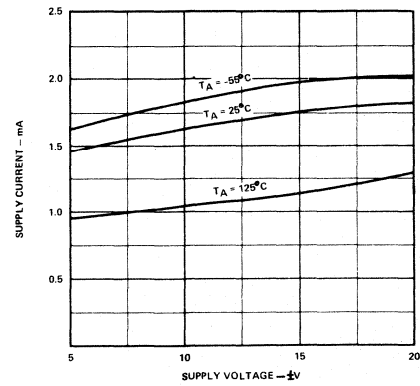
TYPICAL PERFORMANCE CHARACTERISTICS

LM101A/LM201A

VOLTAGE GAIN



SUPPLY CURRENT

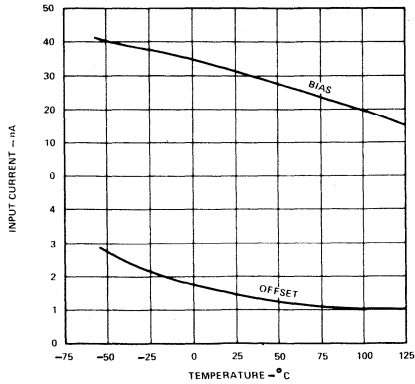




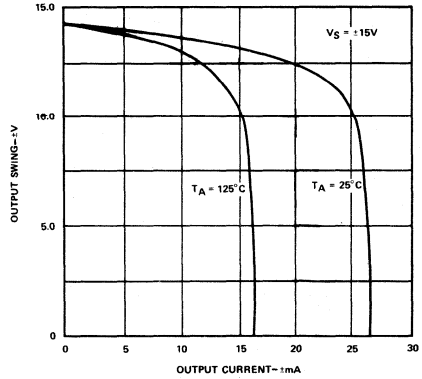
TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)

LM101A/LM201A

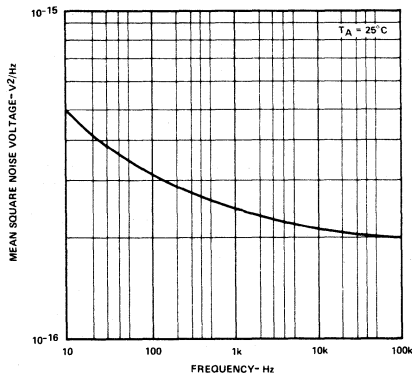
INPUT CURRENT



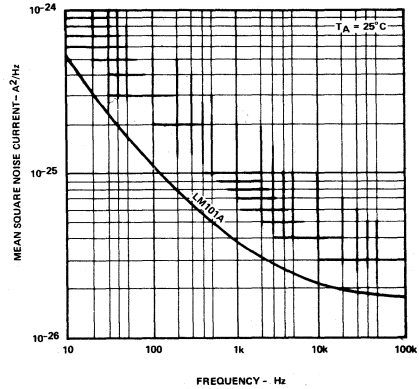
CURRENT LIMITING



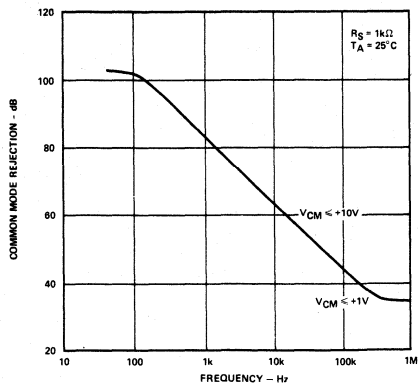
INPUT NOISE VOLTAGE



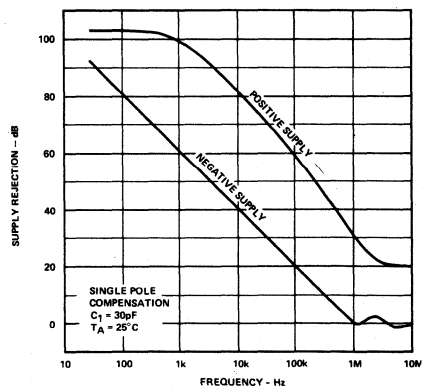
INPUT NOISE CURRENT



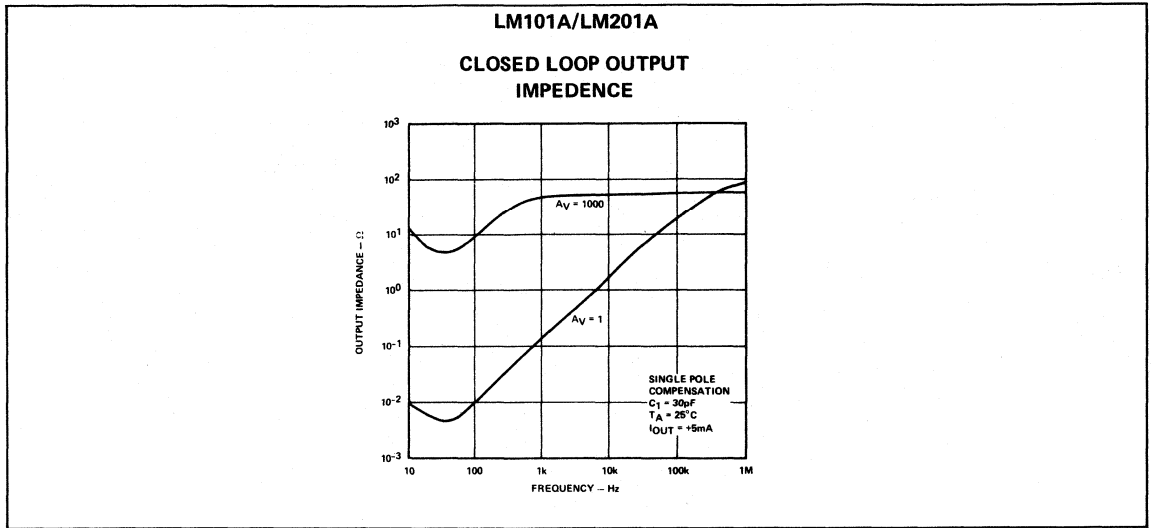
COMMON MODE REJECTION



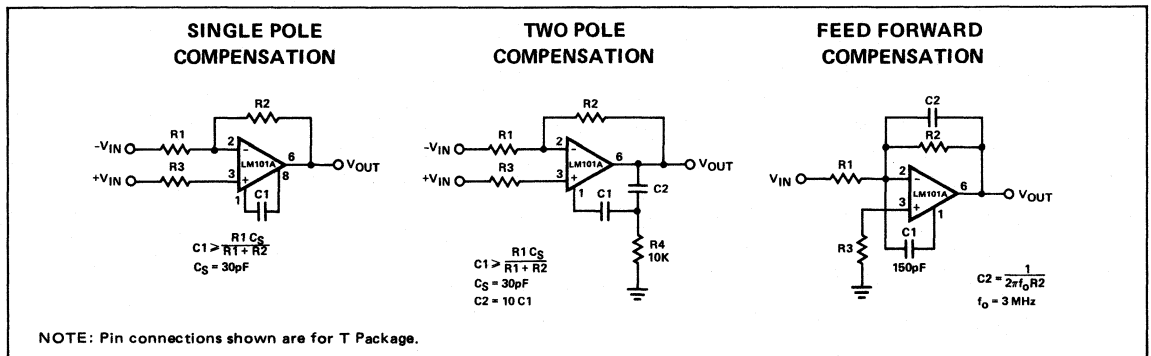
POWER SUPPLY REJECTION



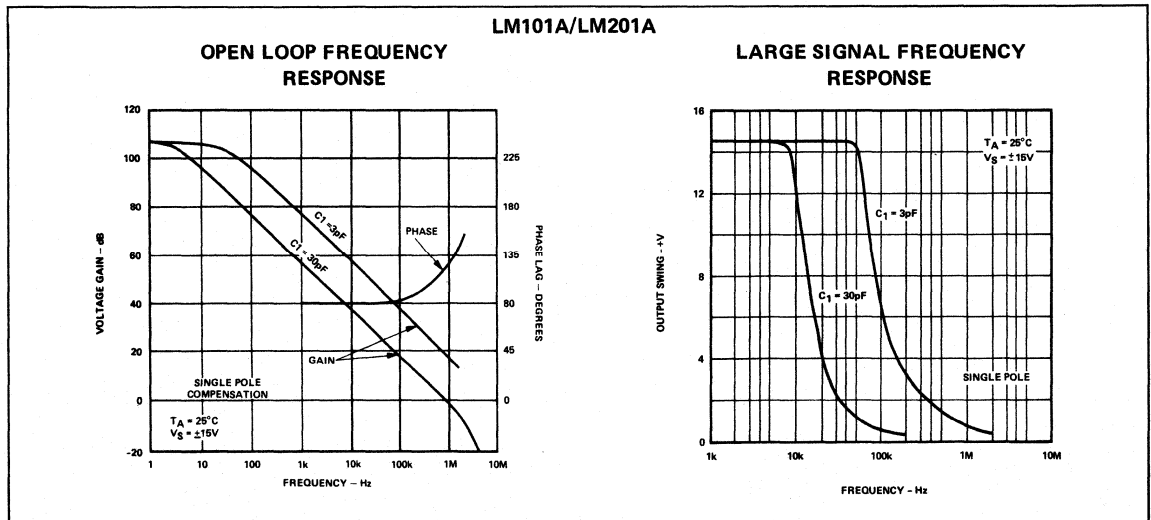
TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)



COMPENSATION CIRCUITS



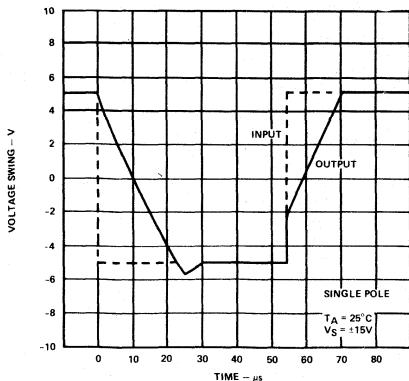
TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)



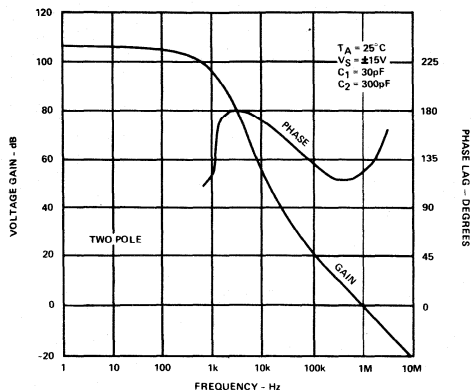
TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)

LM101A/LM201A

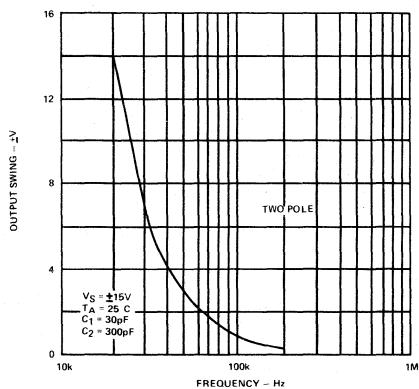
VOLTAGE FOLLOWER PULSE RESPONSE



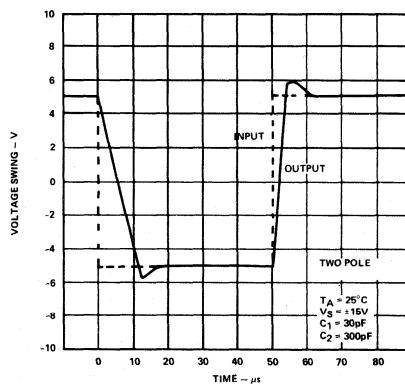
OPEN LOOP FREQUENCY RESPONSE



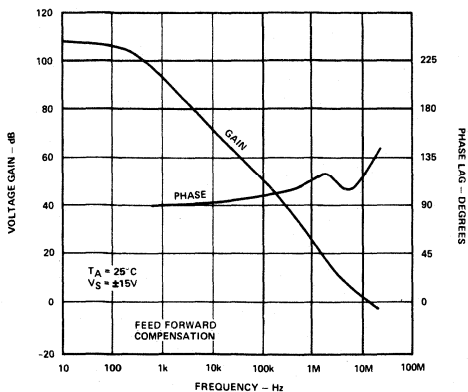
LARGE SIGNAL FREQUENCY RESPONSE



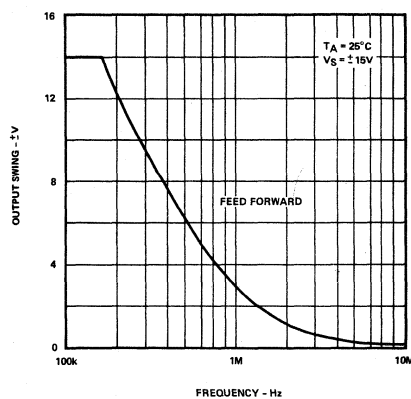
VOLTAGE FOLLOWER PULSE RESPONSE



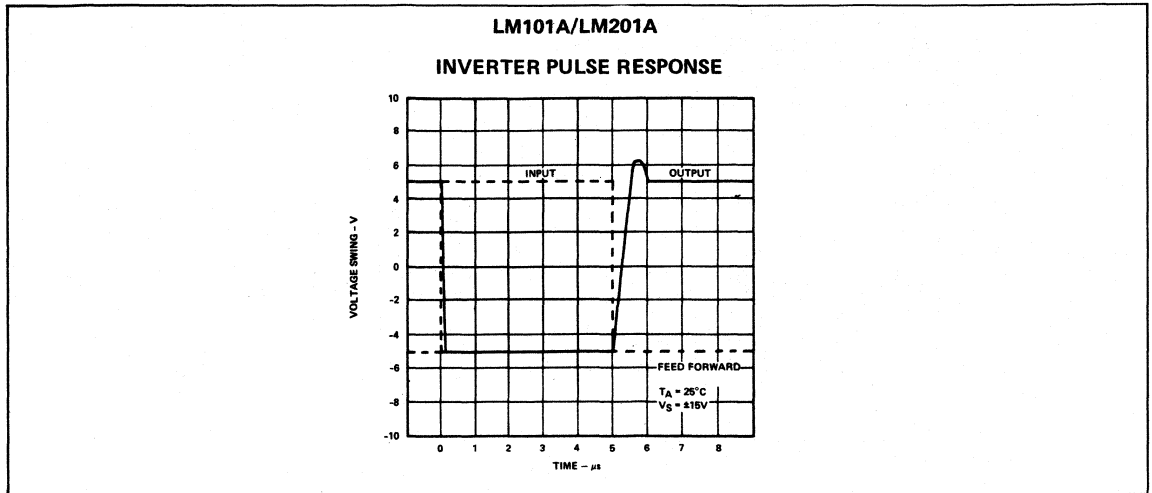
OPEN LOOP FREQUENCY RESPONSE



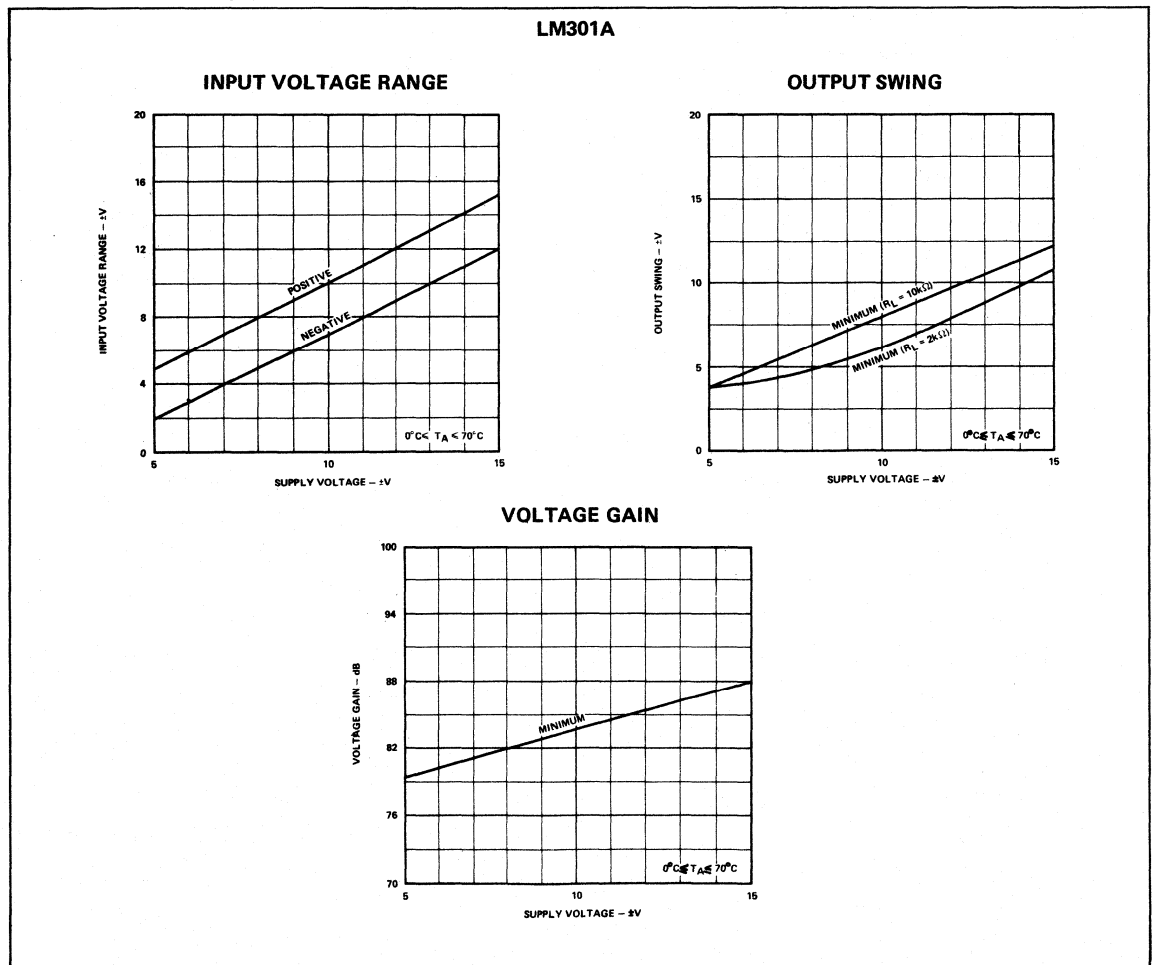
LARGE SIGNAL FREQUENCY RESPONSE



TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)



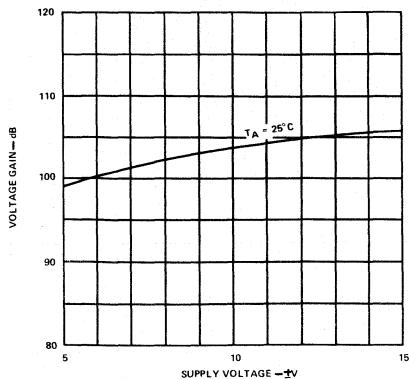
GUARANTEED PERFORMANCE CHARACTERISTICS



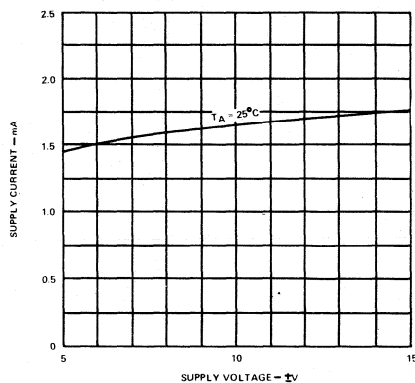
TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)

LM301A

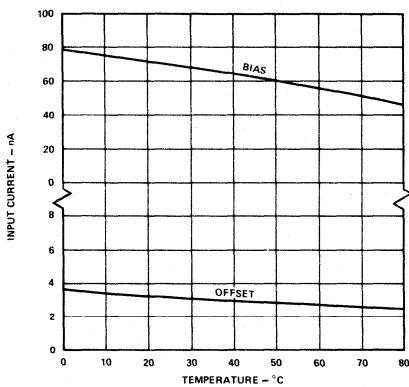
VOLTAGE GAIN



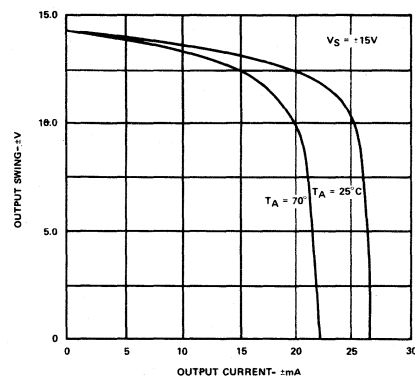
SUPPLY CURRENT



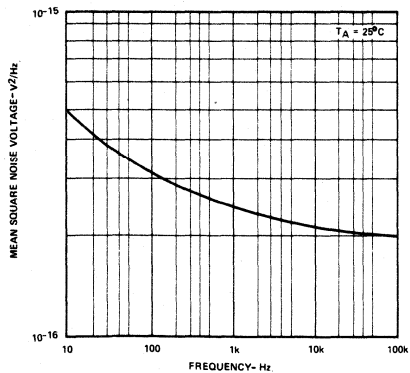
INPUT CURRENT



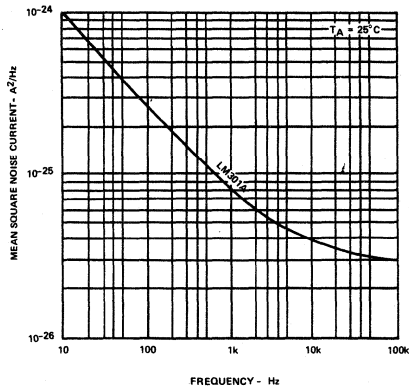
CURRENT LIMITING



INPUT NOISE VOLTAGE



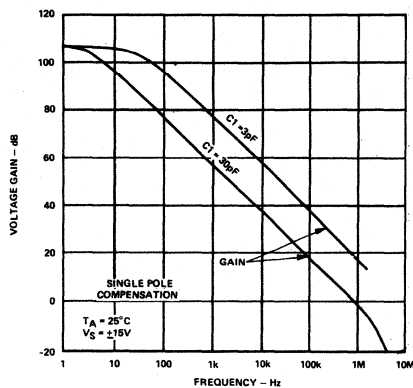
INPUT NOISE CURRENT



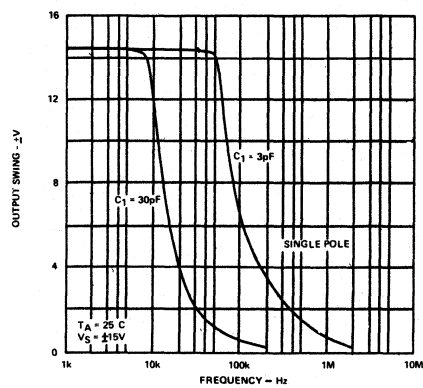
TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)

LM301A

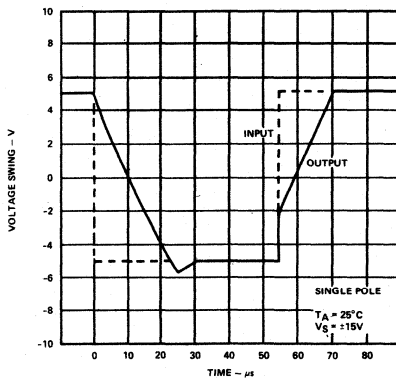
OPEN LOOP FREQUENCY RESPONSE



LARGE SIGNAL FREQUENCY RESPONSE



VOLTAGE FOLLOWER PULSE RESPONSE



### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

The LM101 and LM201 are high performance operational amplifiers featuring high gain, short circuit protection, simplified compensation and excellent temperature stability.

#### FEATURES

- SHORT CIRCUIT PROTECTION
- OFFSET VOLTAGE NULL CAPABILITY
- LARGE COMMON-MODE AND DIFFERENTIAL VOLTAGE RANGES
- LOW POWER CONSUMPTION
- NO LATCH UP

#### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	±22V
Power Dissipation (Note 1)	500mW
Differential Input Voltage	±30V
Input Voltage (Note 2)	±15V

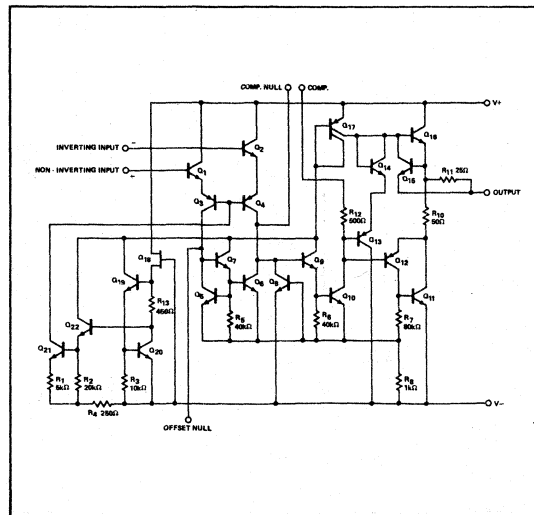
Output Short Circuit Duration	Indefinite
Operating Temperature Range	LM101 -55°C to 125°C
	LM201 0°C to 70°C

Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 60 sec.)	300°C

#### NOTES

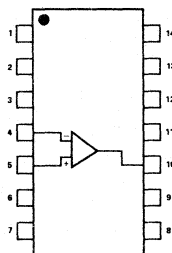
1. Absolute maximum rating holds for all packages. The maximum junction temperature is 150°C for the LM101 and 100°C for the LM201. For operation at elevated temperatures, derate according to appropriate thermal resistances given under package information.
2. For supply voltages less than ±15V, the absolute maximum input voltage is equal to the supply voltage.

#### EQUIVALENT CIRCUIT



#### PIN CONFIGURATIONS (TOP VIEW)

##### A PACKAGE

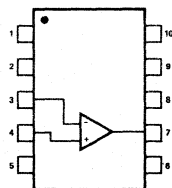


1. NC
2. NC
3. Freq. Comp./Offset Null
4. Inverting Input
5. Noninverting Input
6. V<sup>-</sup>
7. NC
8. NC
9. Offset Null
10. Output
11. V<sup>+</sup>
12. Freq. Comp.
13. NC
14. NC

##### ORDER PART NOS.

LM101N-14	} Silicon	LM101D	} Ceramic
LM201N-14		LM201D	

##### Q PACKAGE

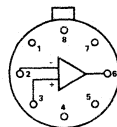


1. NC
2. Bal/Comp
3. Input
4. Input
5. V<sup>-</sup>
6. Bal
7. Output
8. V<sup>+</sup>

##### ORDER PART NOS.

LM101Q/LM201Q

##### T PACKAGE

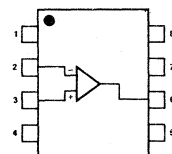


1. Freq. Comp/Offset Null
2. Inverting Input
3. Noninverting Input
4. V<sup>-</sup>
5. Offset Null
6. Output
7. V<sup>+</sup>
8. Freq. Comp.

##### ORDER PART NOS.

LM101H/LM201H

##### V PACKAGE



1. Freq. Comp./Offset Null
2. Inverting Input
3. Noninverting Input
4. V<sup>-</sup>
5. Offset Null
6. Output
7. V<sup>+</sup>
8. Freq. Comp.

##### ORDER PART NO. LM201N

**SIGNETICS HIGH PERFORMANCE AMPLIFIER ■ LM101, LM201**
**ELECTRICAL CHARACTERISTICS** ( $-55^{\circ}\text{C} \leq T_A \leq 125^{\circ}\text{C}$ ,  $\pm 15\text{V} \leq V_S \leq \pm 20\text{V}$  and  $C_1 = 30\text{ pF}$   
 unless otherwise specified)

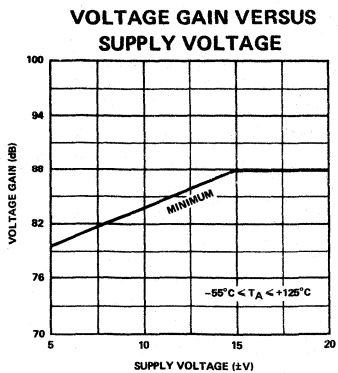
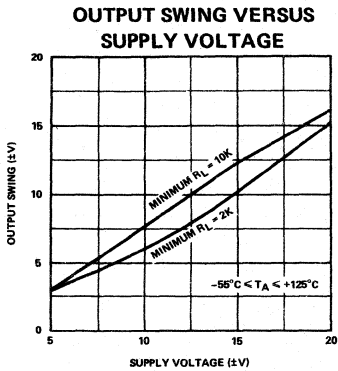
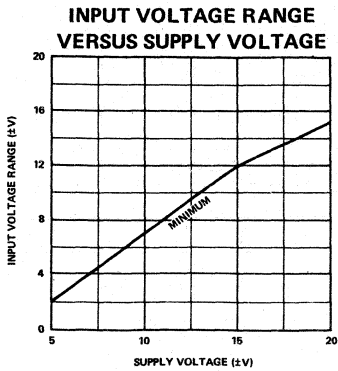
LM101	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNITS
	Input Offset Voltage	$T_A = 25^{\circ}\text{C}$ , $R_S \leq 10\text{ k}\Omega$		1.0	5.0	mV
	Input Offset Current	$T_A = 25^{\circ}\text{C}$		40	200	nA
	Input Bias Current	$T_A = 25^{\circ}\text{C}$		120	500	nA
	Input Resistance	$T_A = 25^{\circ}\text{C}$	300	800		k $\Omega$
	Supply Current	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 20\text{V}$		1.8	3.0	mA
	Large Signal Voltage Gain	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 15\text{V}$ $V_{\text{OUT}} = \pm 10\text{V}$ , $R_L \geq 2\text{ k}\Omega$	50	160		V/mV
	Input Offset Voltage	$R_S \leq 10\text{ k}\Omega$			6.0	mV
	Average Temperature Coefficient of Input Offset Voltage	$R_S \leq 50\Omega$		3.0		$\mu\text{V}/^{\circ}\text{C}$
	Input Offset Current	$R_S \leq 10\text{ k}\Omega$		6.0		$\mu\text{V}/^{\circ}\text{C}$
	Input Offset Current	$T_A = +125^{\circ}\text{C}$ $T_A = -55^{\circ}\text{C}$		10 100	200 500	nA nA
	Input Bias Current	$T_A = -55^{\circ}\text{C}$		0.28	1.5	$\mu\text{A}$
	Supply Current	$T_A = +125^{\circ}\text{C}$ , $V_S = \pm 20\text{V}$		1.2	2.5	mA
	Large Signal Voltage Gain	$V_S = \pm 15\text{V}$ , $V_{\text{OUT}} = \pm 10\text{V}$ $R_L \geq 2\text{ k}\Omega$	25			V/mV
	Output Voltage Swing	$V_S = \pm 15\text{V}$ , $R_L = 10\text{ k}\Omega$ $R_L = 2\text{ k}\Omega$	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$		V V
	Input Voltage Range	$V_S = \pm 15\text{V}$	$\pm 12$			V
	Common Mode Rejection Ratio	$R_S \leq 10\text{ k}\Omega$	70	90		dB
	Supply Voltage Rejection Ratio	$R_S \leq 10\text{ k}\Omega$	70	90		dB

LM201	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNITS
	Input Offset Voltage	$T_A = 25^{\circ}\text{C}$ , $R_S \leq 10\text{ k}\Omega$		2.0	7.5	mV
	Input Offset Current	$T_A = 25^{\circ}\text{C}$		100	500	nA
	Input Bias Current	$T_A = 25^{\circ}\text{C}$		0.25	1.5	$\mu\text{A}$
	Input Resistance	$T_A = 25^{\circ}\text{C}$	100	400		k $\Omega$
	Supply Current	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 20\text{V}$		1.8	3.0	mA
	Large Signal Voltage Gain	$T_A = 25^{\circ}\text{C}$ , $V_S = \pm 15\text{V}$ $V_{\text{OUT}} = \pm 10\text{V}$ , $R_L \geq 2\text{ k}\Omega$	20	150		V/mV
	Input Offset Voltage	$R_S \leq 10\text{ k}\Omega$			10	mV
	Average Temperature Coefficient of Input Offset Voltage	$R_S \leq 50\Omega$		6		$\mu\text{V}/^{\circ}\text{C}$
	Input Offset Current	$R_S \leq 10\text{ k}\Omega$		10		$\mu\text{V}/^{\circ}\text{C}$
	Input Offset Current	$T_A = +70^{\circ}\text{C}$ $T_A = 0^{\circ}\text{C}$		50 150	400 750	nA nA
	Input Bias Current	$T_A = 0^{\circ}\text{C}$		0.32	2.0	$\mu\text{A}$
	Large Signal Voltage Gain	$V_S = \pm 15\text{V}$ , $V_{\text{OUT}} = \pm 10\text{V}$ $R_L \geq 2\text{ k}\Omega$	15			V/mV
	Output Voltage Swing	$V_S = \pm 15\text{V}$ , $R_L = 10\text{ k}\Omega$ $R_L = 2\text{ k}\Omega$	$\pm 12$ $\pm 10$	$\pm 14$ $\pm 13$		V V
	Input Voltage Range	$V_S = \pm 15\text{V}$	$\pm 12$			V
	Common Mode Rejection Ratio	$R_S \leq 10\text{ k}\Omega$	65	90		dB
	Supply Voltage Rejection Ratio	$R_S \leq 10\text{ k}\Omega$	70	90		dB

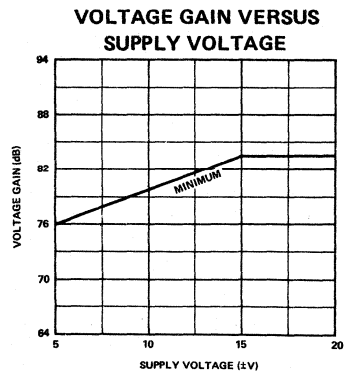
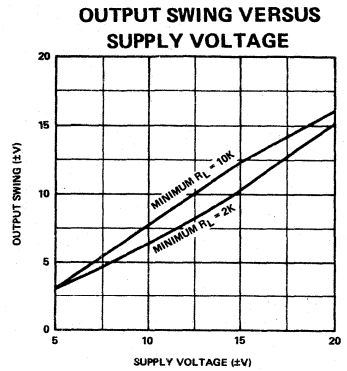
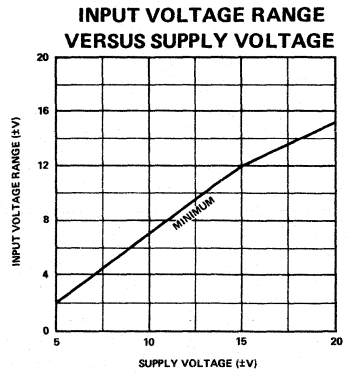


TYPICAL CHARACTERISTIC CURVES

LM101



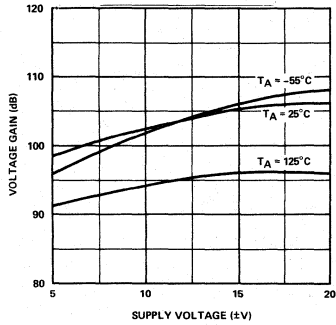
LM201



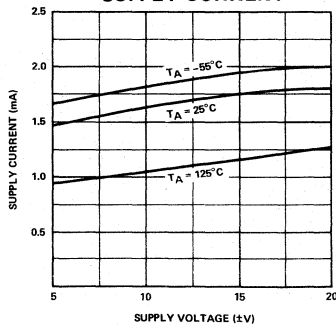
TYPICAL CHARACTERISTIC CURVES (Cont'd.)

LM101

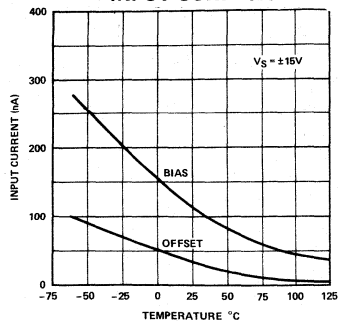
VOLTAGE GAIN



SUPPLY CURRENT

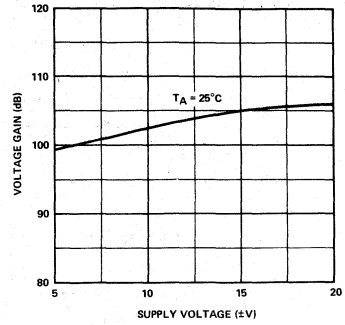


INPUT CURRENT

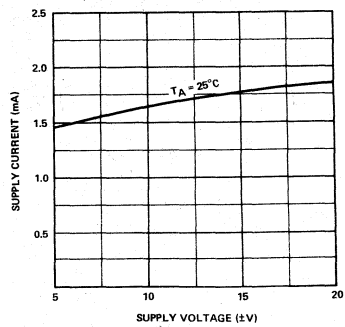


LM201

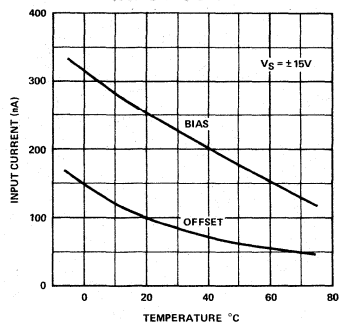
VOLTAGE GAIN



SUPPLY CURRENT

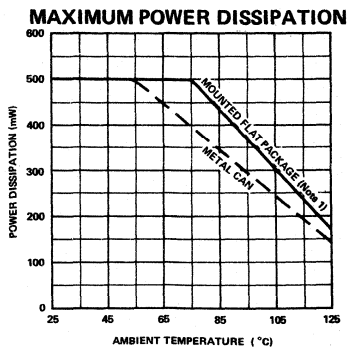
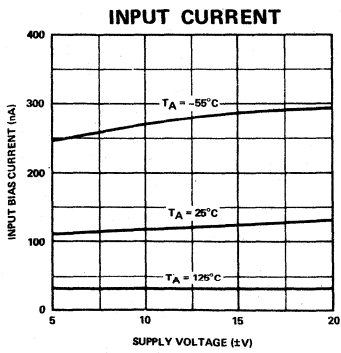
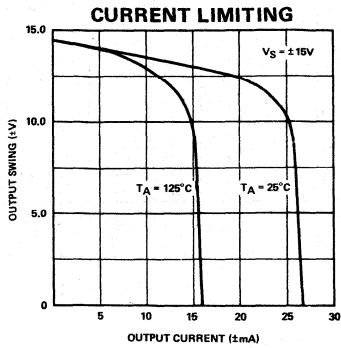


INPUT CURRENT

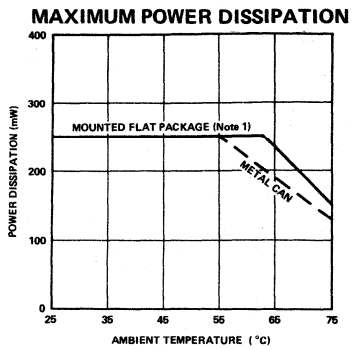
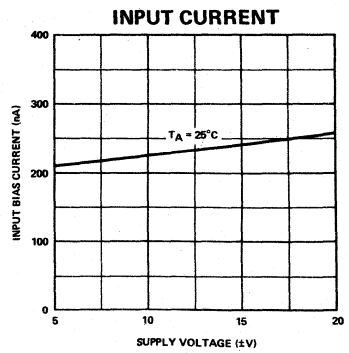
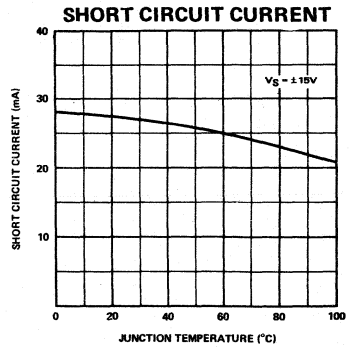


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

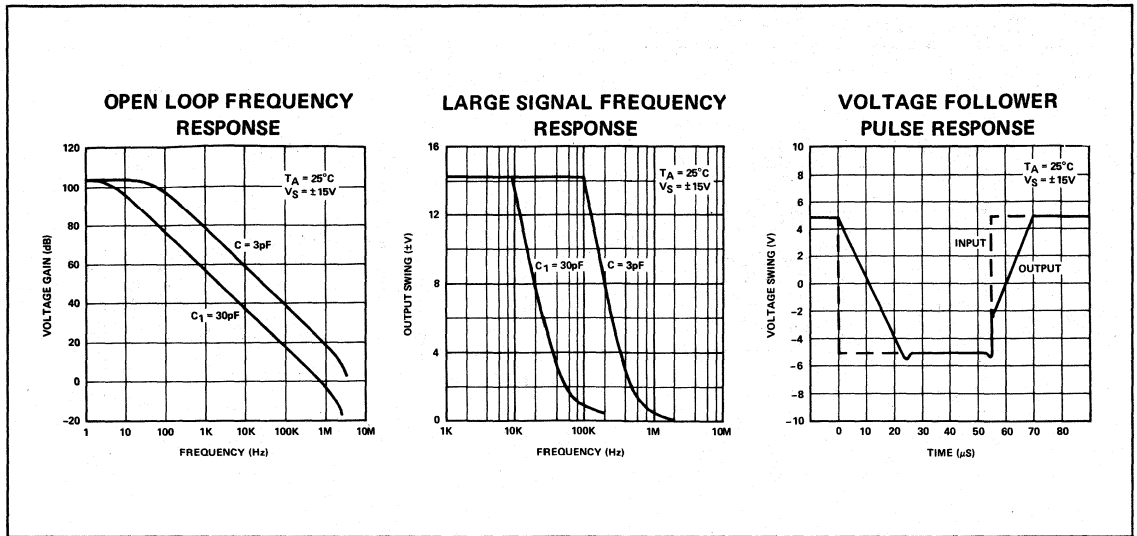
LM101



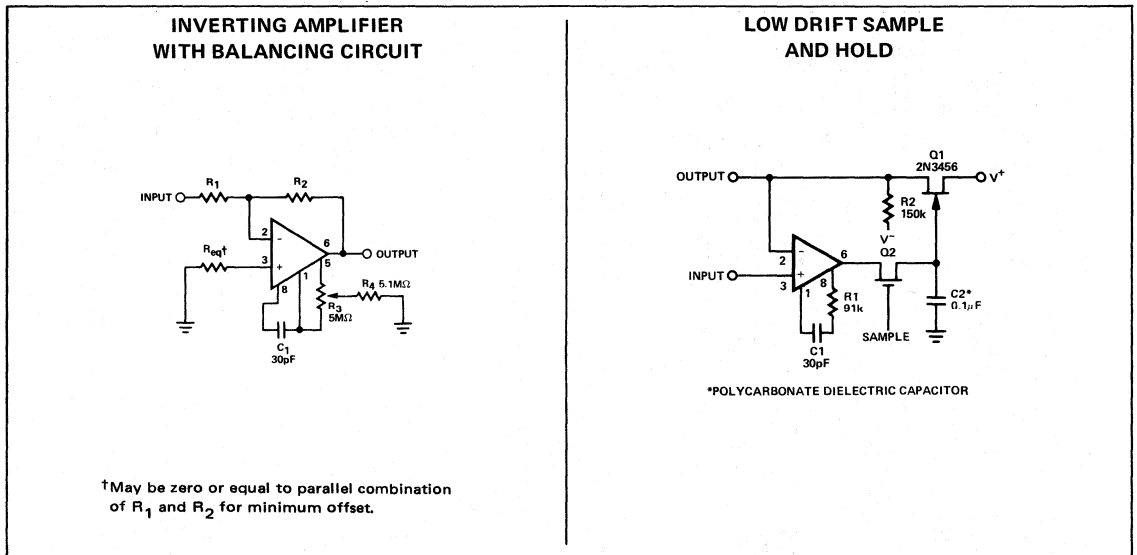
LM201



TYPICAL CHARACTERISTIC CURVES (Cont'd.)



TYPICAL APPLICATIONS (Pin numbers shown refer to T or V package only)



† May be zero or equal to parallel combination of  $R_1$  and  $R_2$  for minimum offset.

### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

The LM107/207/307 is a general purpose internally compensated operational amplifier. Advanced processing techniques provide input currents which are an order of magnitude lower than the  $\mu A709$ . Standard pin out allows plug in replacement for the  $\mu A709$ , LM101, LM101A, and the  $\mu A741$ .

#### FEATURES

- 3mV MAX OFFSET VOLTAGE OVER TEMP
- 100 nA MAX INPUT CURRENT OVER TEMP
- 20 nA MAX INPUT OFFSET CURRENT OVER TEMP
- OFFSETS GUARANTEED OVER COMMON MODE RANGE
- INPUT/OUTPUT SHORT CIRCUIT PROTECTED

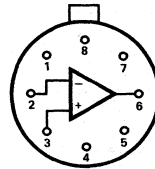
#### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	LM107	$\pm 22V$
	LM307	$\pm 18V$
Power Dissipation (Note 1)		500 mW
Differential Input Voltage		$\pm 30V$
Input Voltage (Note 2)		$\pm 15V$
Output Short-Circuit Duration (Note 3)		Indefinite
Operating Temperature Range	LM107	$-55^{\circ}C$ to $125^{\circ}C$
	LM207	$-25^{\circ}C$ to $85^{\circ}C$
	LM307	$0^{\circ}C$ to $70^{\circ}C$
Storage Temperature Range		$-65^{\circ}C$ to $150^{\circ}C$
Lead Temperature (Soldering, 60 sec)		$300^{\circ}C$

#### EQUIVALENT SCHEMATIC

#### PIN CONFIGURATIONS (TOP VIEW)

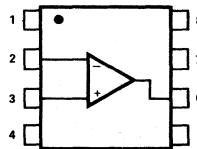
##### T PACKAGE



1. NC
2. Inverting Input
3. Noninverting Input
4.  $V^-$
5. NC
6. Output
7.  $V^+$
8. NC

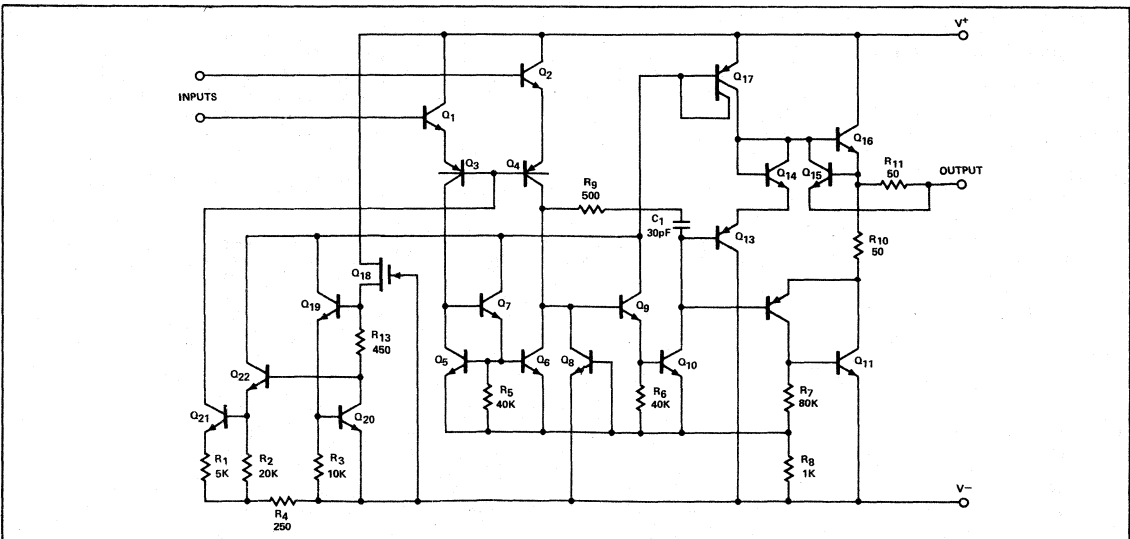
ORDER PART NOS.  
LM107H/LM207H/LM307H

##### V PACKAGE



1. NC
2. Inverting Input
3. Noninverting Input
4.  $V^-$
5. NC
6. Output
7.  $V^+$
8. NC

ORDER PART NO.  
LM107N/LM207N/LM307N



**SIGNETICS GENERAL PURPOSE OPERATIONAL AMP ■ LM107, LM207, LM307**
**ELECTRICAL CHARACTERISTICS**

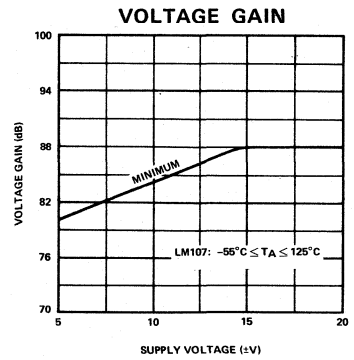
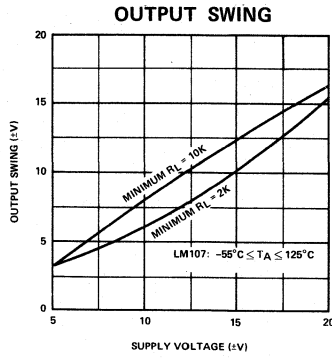
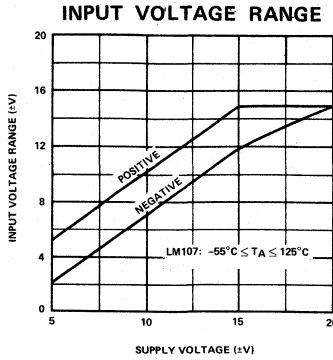
PARAMETER	CONDITIONS	LM101/207			LM307			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Input Offset Voltage	$T_A = 25^\circ\text{C}, R_S \leq 10\text{K}\Omega$	—	0.7	2.0	—	—	—	mV
	$T_A = 25^\circ\text{C}, R_S \leq 50\text{K}\Omega$	—	—	—	—	2.0	7.5	—
Input Offset Current	$T_A = 25^\circ\text{C}$	—	1.5	10	—	3	50	nA
Input Bias Current	$T_A = 25^\circ\text{C}$	—	30	75	—	70	250	nA
Input Resistance	$T_A = 25^\circ\text{C}$	1.5	4	—	0.5	2	—	M $\Omega$
Supply Current	$T_A = 25^\circ\text{C}, V_S = \pm 20\text{V}$	—	1.8	3.0	—	—	—	mA
	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$	—	—	—	—	1.8	3.0	mA
Large Signal Voltage Gain	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$ $V_{\text{OUT}} = \pm 10\text{V}$ , $R_L \geq 2\text{K}\Omega$	50	160	—	25	160	—	V/mV
Input Offset Voltage	$R_S \leq 10\text{K}\Omega$	—	—	3.0	—	—	—	mV
	$R_S \leq 50\text{K}\Omega$	—	—	—	—	—	10	mV
Average Temperature Coefficient of Input Offset Voltage			3.0	15	—	6.0	30	$\mu\text{V}/^\circ\text{C}$
Input Offset Current		—	—	20	—	—	70	nA
Average Temperature Coefficient of Input Offset Current	$25^\circ\text{C} \leq T_A \leq 125^\circ\text{C}$	—	0.01	0.1	—	—	—	$\text{nA}/^\circ\text{C}$
	$-55^\circ\text{C} \leq T_A \leq 25^\circ\text{C}$	—	0.02	0.2	—	—	—	$\text{nA}/^\circ\text{C}$
Average Temperature Coefficient of Input Offset Current	$25^\circ\text{C} \leq T_A \leq 70^\circ\text{C}$	—	—	—	—	0.01	0.3	$\text{nA}/^\circ\text{C}$
	$0^\circ\text{C} \leq T_A \leq 25^\circ\text{C}$	—	—	—	—	0.02	0.6	$\text{nA}/^\circ\text{C}$
Input Bias Current		—	—	100	—	—	300	nA
Supply Current	$T_A = +125^\circ\text{C}$ , $V_S = \pm 20\text{V}$	—	1.2	2.5	—	—	—	mA
Large Signal Voltage Gain	$V_S = \pm 15\text{V}, V_{\text{OUT}} = \pm 10\text{V}, R_L \geq 2\text{K}\Omega$	25	—	—	15	—	—	V/mV
Output Voltage Swing	$V_S = \pm 15\text{V}, R_L = 10\text{K}\Omega$	$\pm 12$	$\pm 14$	—	$\pm 12$	$\pm 14$	—	V
	$R_L = 2\text{K}\Omega$	$\pm 10$	$\pm 13$	—	$\pm 10$	$\pm 13$	—	V
Input Voltage Range	$V_S = \pm 20\text{V}$	$\pm 15$	—	—	—	—	—	V
	$V_S = \pm 15\text{V}$	—	—	—	$\pm 12$	—	—	V
Common Mode Rejection Ratio	$R_S \leq 10\text{K}\Omega$	80	96	—	—	—	—	dB
	$R_S \leq 50\text{K}\Omega$	—	—	—	70	90	—	dB
Supply Voltage Rejection Ratio	$R_S \leq 10\text{K}\Omega$	80	96	—	—	—	—	dB
	$R_S \leq 50\text{K}\Omega$	—	—	—	70	96	—	dB

**NOTES:**

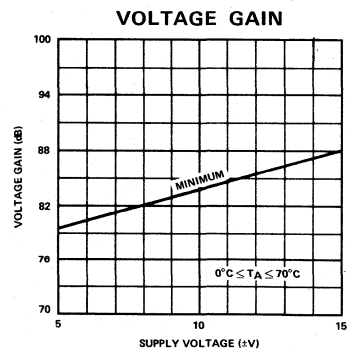
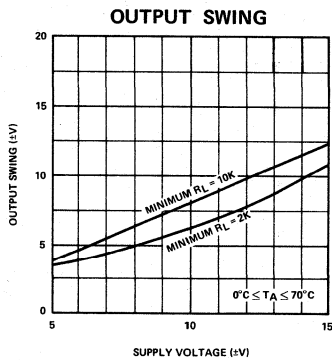
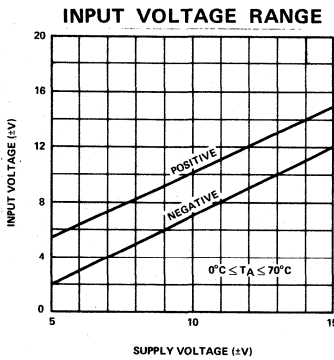
- For operating at elevated temperatures, the device must be derated based on a  $150^\circ\text{C}$  maximum junction temperature and a thermal resistance of  $150^\circ\text{C}/\text{W}$  junction to ambient or  $45^\circ\text{C}/\text{W}$  junction to case (for T Package).
- For supply voltages less than  $\pm 15\text{V}$ , the absolute maximum input voltage is equal to the supply voltage.
- Continuous short circuit is allowed for case temperatures to  $70^\circ\text{C}$  and ambient temperatures to  $55^\circ\text{C}$ .
- The specifications apply for  $-55^\circ\text{C}$  to  $125^\circ\text{C}$  for LM107 and  $0^\circ\text{C}$  to  $70^\circ\text{C}$  for LM307 unless otherwise specified.
- $\pm 5\text{V} < V_S \leq \pm 15\text{V}$  unless otherwise specified.

GUARANTEED PERFORMANCE CURVES

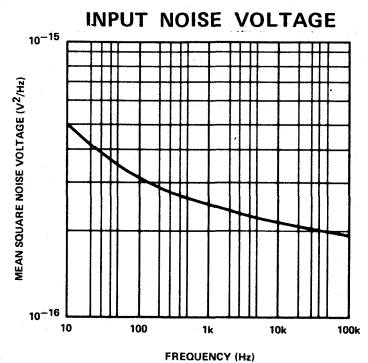
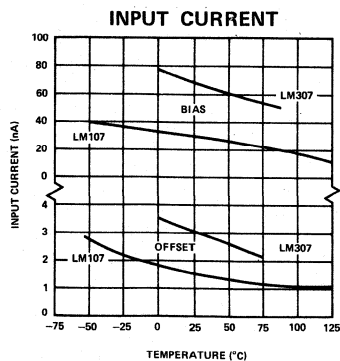
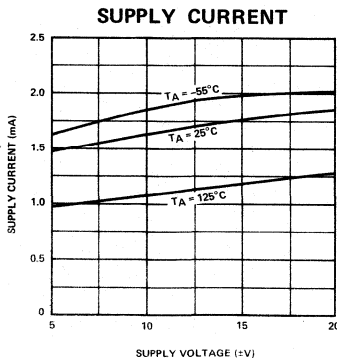
LM107/207



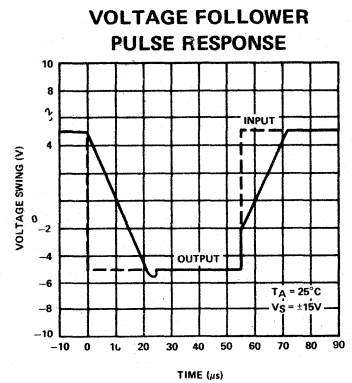
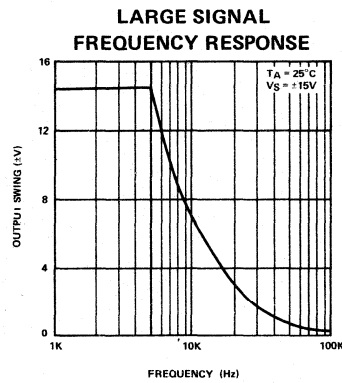
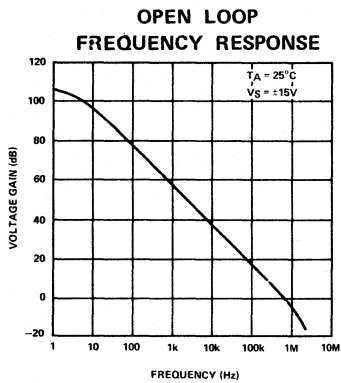
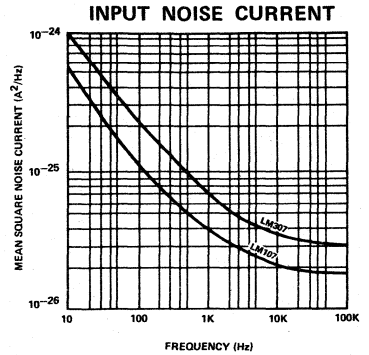
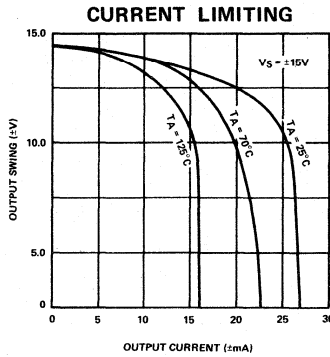
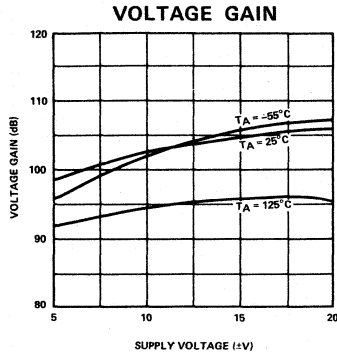
LM307



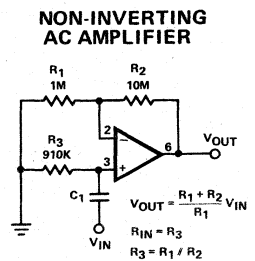
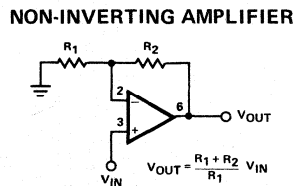
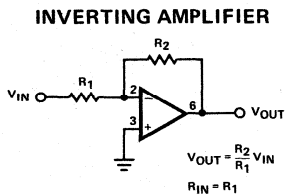
TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES (cont'd)



TYPICAL APPLICATIONS





## DESCRIPTION

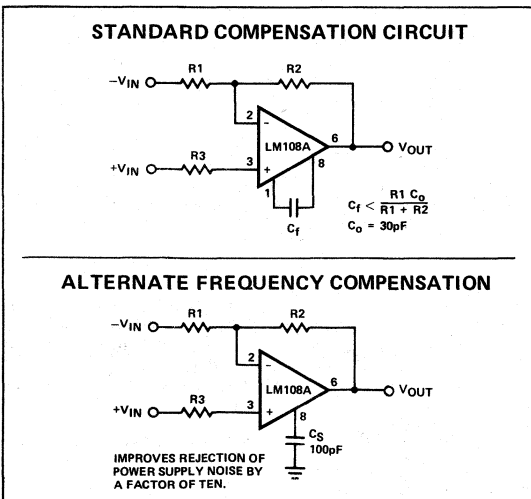
The LM108A, LM208A and LM308A are precision operational amplifiers having specifications about a factor of ten better than FET amplifiers over their operating range. In addition to low input currents, these devices have extremely low offset voltage, making it possible to eliminate offset adjustments, in most cases, and obtain performance approaching chopper stabilized amplifiers.

The devices operate with supply voltages from  $\pm 2V$  to  $\pm 20V$  and have sufficient supply rejection to use unregulated supplies. Although the circuit is interchangeable with and uses the same compensation as the LM101A, an alternate compensation scheme can be used to make it particularly insensitive to power supply noise and to make supply bypass capacitors unnecessary.

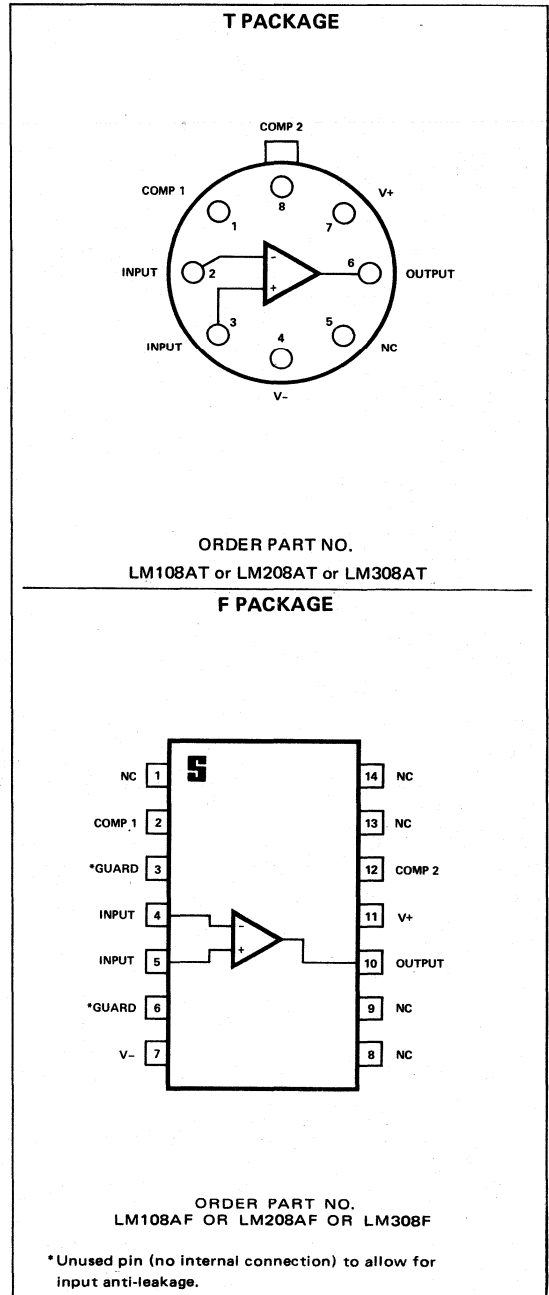
## FEATURES

- OFFSET VOLTAGE GUARANTEED LESS THAN 0.5 mV
- MAXIMUM INPUT BIAS CURRENT OF 3.0 nA OVER TEMPERATURE
- OFFSET CURRENT LESS THAN 400 pA OVER TEMPERATURE
- SUPPLY CURRENT OF ONLY 300  $\mu A$ , EVEN IN SATURATION
- GUARANTEED 5  $\mu V/^{\circ}C$  DRIFT.

## COMPENSATION CIRCUITS



## PIN CONFIGURATION (Top View)



# SIGNETICS PRECISION OPERATIONAL AMPLIFIER ■ LM108A, LM208A, LM308A

## ABSOLUTE MAXIMUM RATINGS LM108A, LM208A

Supply Voltage	±20V
Power Dissipation (Note 1)	500 mW
Differential Input Current (Note 2)	±10 mA
Input Voltage (Note 3)	±15V
Output Short-Circuit Duration	Indefinite
Operating Temperature Range LM108A	-55°C to 125°C
LM208A	-25°C to 85°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

## ELECTRICAL CHARACTERISTICS (See Note 4)

LM108A/LM208A					
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage (Note 5)	$T_A = 25^\circ\text{C}$		0.3	0.5	mV
Input Offset Current	$T_A = 25^\circ\text{C}$		0.05	0.2	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		0.8	2.0	nA
Input Resistance	$T_A = 25^\circ\text{C}$	30	70		MΩ
Supply Current	$T_A = 25^\circ\text{C}$		0.3	0.6	mA
Large Signal Voltage Gain	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$ $V_{\text{OUT}} = \pm 10\text{V}, R_L \geq 10\text{ k}\Omega$	80	300		V/mV
Input Offset Voltage (Note 5)				1.0	mV
Average Temperature Coefficient of Input Offset Voltage (Note 5)			1.0	5.0	$\mu\text{V}/^\circ\text{C}$
Input Offset Current				0.4	nA
Average Temperature Coefficient of Input Offset Current			0.5	2.5	$\text{pA}/^\circ\text{C}$
Input Bias Current				3.0	nA
Supply Current	$T_A = +125^\circ\text{C}$		0.15	0.4	mA
Large Signal Voltage Gain	$V_S = \pm 15\text{V}, V_{\text{OUT}} = \pm 10\text{V}$ $R_L \geq 10\text{ k}\Omega$	40			V/mV
Output Voltage Swing	$V_S = \pm 15\text{V}, R_L = 10\text{ k}\Omega$	±13	±14		V
Input Voltage Range	$V_S = \pm 15\text{V}$	±13.5			V
Common Mode Rejection Ratio		96	110		dB
Supply Voltage Rejection Ratio		96	110		dB

### NOTES

- The maximum junction temperature of the LM108A is 150°C, while that of the LM208A is 100°C. For operating at elevated temperatures, devices in the TO-5 package must be derated based on a thermal resistance of 150°C/W, junction to ambient, or 45°C/W, junction to case. For the flat package, the derating is based on a thermal resistance of 185°C/W when mounted on a 1/16-inch-thick epoxy glass board with ten, 0.03-inch-wide, 2-ounce copper conductors. The thermal resistance of the dual-in-line package is 100°C/W, junction to ambient.
- The inputs are shunted with back-to-back diodes for overvoltage protection. Therefore, excessive current will flow if a differential input voltage in excess of 1V is applied between the inputs unless some limiting resistance is used.
- For supply voltages less than ±15V, the absolute maximum input voltage is equal to the supply voltage.
- These specifications apply for  $\pm 5\text{V} \leq V_S \leq \pm 20\text{V}$  and  $-55^\circ\text{C} \leq T_A \leq 125^\circ\text{C}$ , unless otherwise specified. With the LM208A, however, all temperature specifications are limited to  $-25^\circ\text{C} \leq T_A \leq 85^\circ\text{C}$ .
- The LM 108A has a guaranteed offset voltage less than 0.5 mV at 25°C and 1.0 mV for  $-55^\circ\text{C} \leq T_A \leq 125^\circ\text{C}$  and  $V_S = \pm 15\text{V}$ . The average temperature coefficient of input offset voltage is guaranteed to be less than 5  $\mu\text{V}/^\circ\text{C}$  for these same conditions.

## ABSOLUTE MAXIMUM RATINGS LM308A

Supply Voltage	±18V
Power Dissipation (Note 1)	500 mW
Differential Input Current (Note 2)	±10 mA
Input Voltage (Note 3)	±15V
Output Short-Circuit Duration	Indefinite
Operating Temperature Range	0°C to 70°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

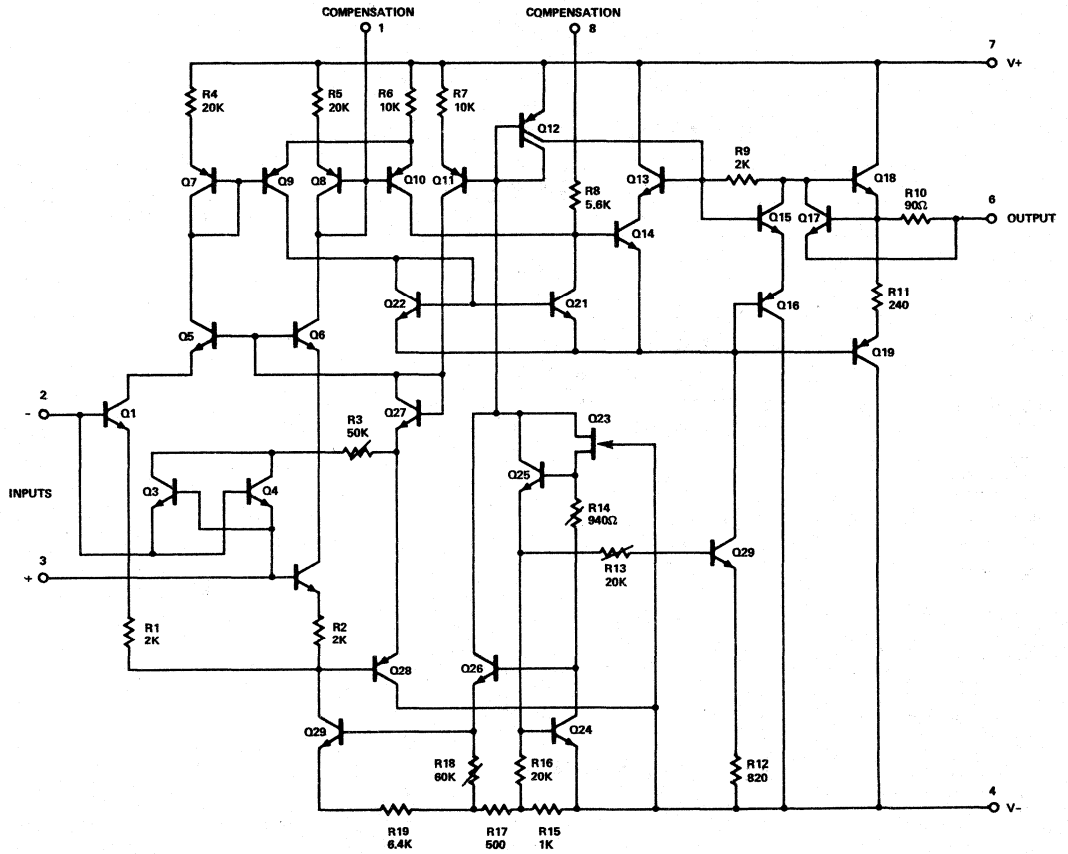
## ELECTRICAL CHARACTERISTICS (See Note 4)

LM308A					
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	$T_A = 25^\circ\text{C}$		0.3	0.5	mV
Input Offset Current	$T_A = 25^\circ\text{C}$		0.2	1	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		1.5	7	nA
Input Resistance	$T_A = 25^\circ\text{C}$	10	40		M $\Omega$
Supply Current	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$		0.3	0.8	mA
Large Signal Voltage Gain	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$ $V_{\text{OUT}} = \pm 10\text{V}, R_L \geq 10\text{ k}\Omega$	80	300		V/mV
Input Offset Voltage				0.73	mV
Average Temperature Coefficient of Input Offset Voltage			1.0	5.0	$\mu\text{V}/^\circ\text{C}$
Input Offset Current				1.5	nA
Average Temperature Coefficient of Input Offset Current			2.0	10	$\text{pA}/^\circ\text{C}$
Input Bias Current				10	nA
Large Signal Voltage Gain	$V_S = \pm 15\text{V}, V_{\text{OUT}} = \pm 10\text{V}$ $R_L > 10\text{ k}\Omega$	60			V/mV
Output Voltage Swing	$V_S = \pm 15\text{V}, R_L = 10\text{ k}\Omega$	±13	±14		V
Input Voltage Range	$V_S = \pm 15\text{V}$	±14			V
Common Mode Rejection Ratio		96	110		dB
Supply Voltage Rejection Ratio		96	110		dB

## NOTES

- The maximum junction temperature of the LM308A is 85°C. For operating at elevated temperatures, devices in the TO-5 package must be derated based on a thermal resistance of 150°C/W, junction to ambient, or 45°C/W, junction to case. For the flat package, the derating is based on a thermal resistance of 185°C/W when mounted on a 1/16-inch-thick epoxy glass board with ten, 0.03-inch-wide, 2-ounce copper conductors. The thermal resistance of the dual-in-line package is 100°C/W, junction to ambient.
- The inputs are shunted with back-to-back diodes for overvoltage protection. Therefore, excessive current will flow if a differential input voltage in excess of 1V is applied between the inputs unless some limiting resistance is used.
- For supply voltages less than ±15V, the absolute maximum input voltage is equal to the supply voltage.
- These specifications apply for  $\pm 5\text{V} < V_S < \pm 15\text{V}$  and  $0^\circ\text{C} < T_A < 70^\circ\text{C}$ , unless otherwise specified.

SCHEMATIC DIAGRAM



NOTE: Pin numbers for T Package.

### DESCRIPTION

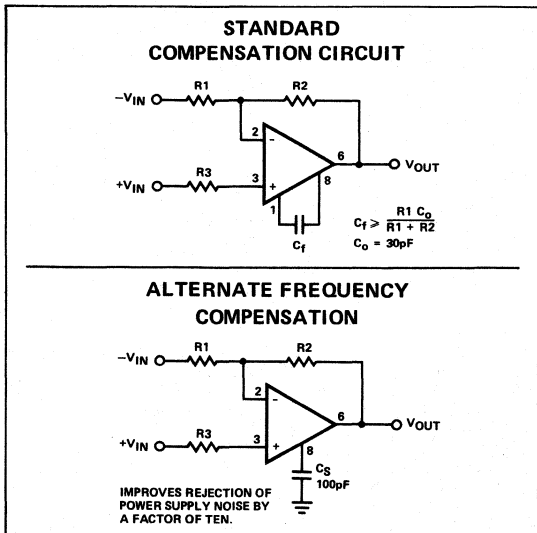
The LM108 and LM208 are precision operational amplifiers having specifications a factor of ten better than FET amplifiers over a  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$  temperature range. Selected units are available with offset voltages less than 1.0 mV and drifts less than  $5 \mu\text{V}/^{\circ}\text{C}$ , again over the military temperature range. This makes it possible to eliminate offset adjustments, in most cases, and obtain performance approaching chopper stabilized amplifiers.

The devices operate with supply voltages from  $\pm 2\text{V}$  to  $\pm 20\text{V}$  and have sufficient supply rejection to use unregulated supplies. Although the circuit is interchangeable with and uses the same compensation as the LM101A, an alternate compensation scheme can be used to make it particularly insensitive to power supply noise and to make supply bypass capacitors unnecessary.

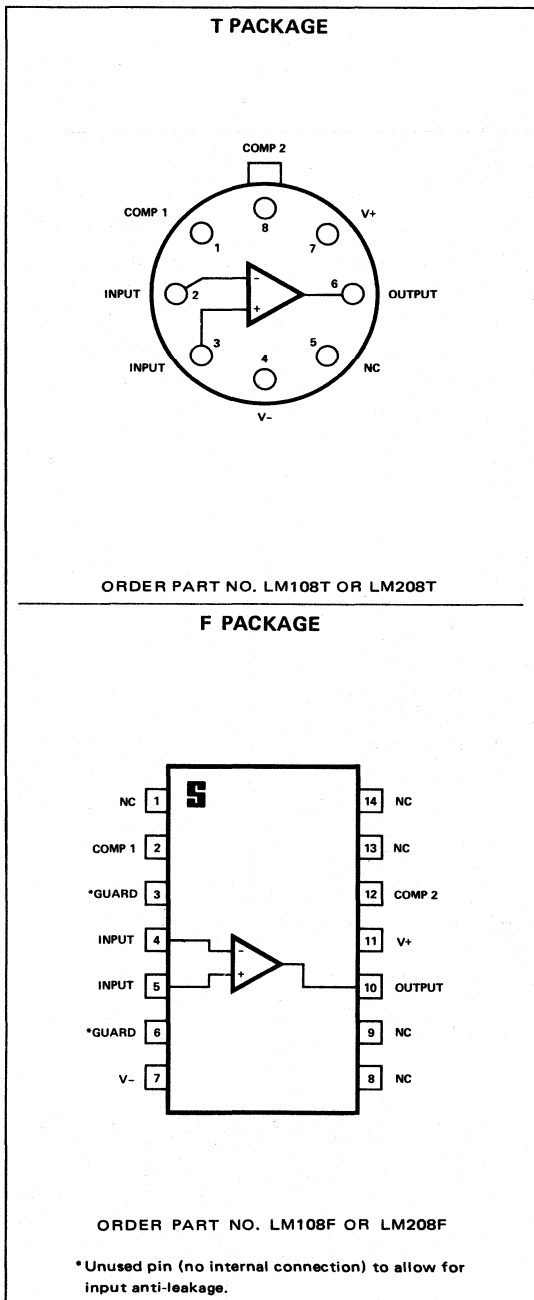
### FEATURES

- MAXIMUM INPUT BIAS CURRENT OF 3.0 nA OVER TEMPERATURE
- OFFSET CURRENT LESS THAN 400 pA OVER TEMPERATURE
- SUPPLY CURRENT OF ONLY 300  $\mu\text{A}$ , EVEN IN SATURATION
- GUARANTEED DRIFT CHARACTERISTICS

### COMPENSATION CIRCUITS



### PIN CONFIGURATION (Top Views)



**ABSOLUTE MAXIMUM RATINGS LM108/LM208**

Supply Voltage	±20V
Power Dissipation (Note 1)	500 mW
Differential Input Current (Note 2)	±10 mA
Input Voltage (Note 3)	±15V
Output Short-Circuit Duration	Indefinite
Operating Temperature Range LM108	-55°C to 125°C
LM208	-25°C to 85°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 60 sec)	300°C

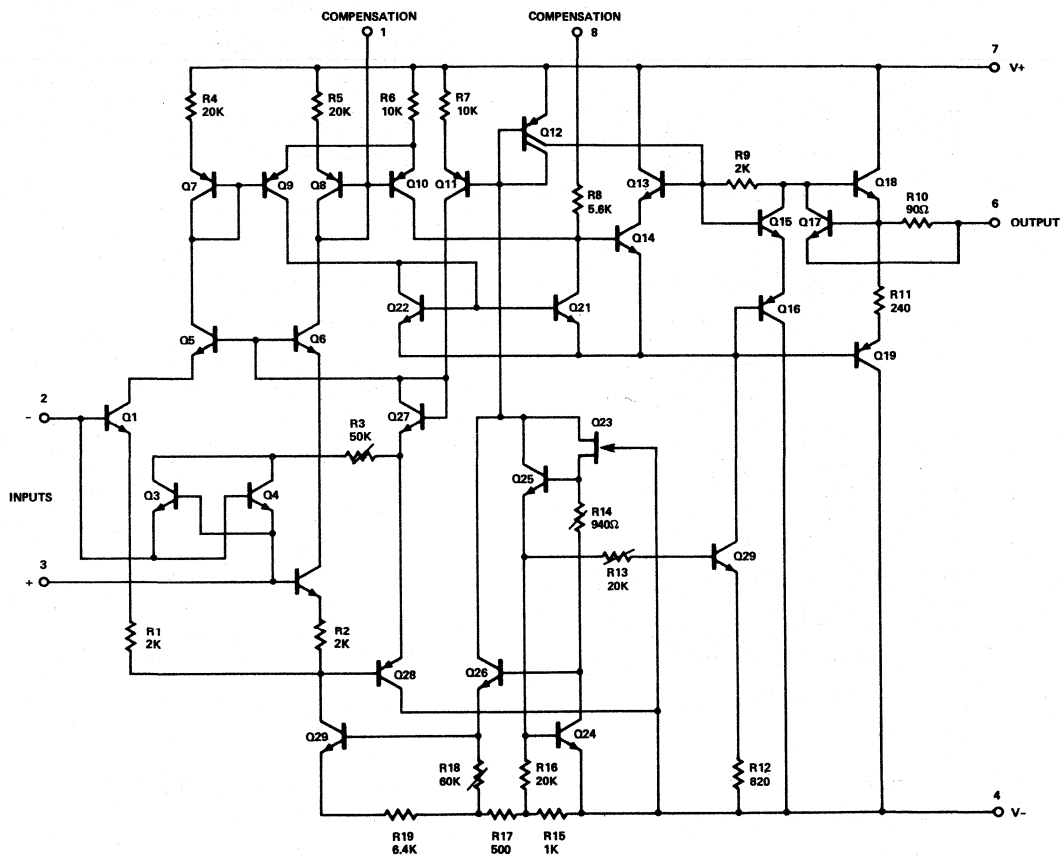
**ELECTRICAL CHARACTERISTICS (See Note 4)**

LM108/LM208					
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage (Note 5)	T <sub>A</sub> = 25°C		0.7	2.0	mV
Input Offset Current	T <sub>A</sub> = 25°C		0.05	0.2	nA
Input Bias Current	T <sub>A</sub> = 25°C		0.8	2.0	nA
Input Resistance	T <sub>A</sub> = 25°C	30	70		MΩ
Supply Current	T <sub>A</sub> = 25°C		0.3	0.6	mA
Large Signal Voltage Gain	T <sub>A</sub> = 25°C, V <sub>S</sub> = ±15V V <sub>OUT</sub> = ±10V, R <sub>L</sub> ≥ 10 kΩ	50	300		V/mV
Input Offset Voltage (Note 5)				3.0	mV
Average Temperature Coefficient of Input Offset Voltage (Note 5)			3.0	15	μV/°C
Input Offset Current				0.4	nA
Average Temperature Coefficient of Input Offset Current			0.5	2.5	pA/°C
Input Bias Current				3.0	nA
Supply Current	T <sub>A</sub> = +125°C		0.15	0.4	mA
Large Signal Voltage Gain	V <sub>S</sub> = ±15V, V <sub>OUT</sub> = ±10V R <sub>L</sub> ≥ 10 kΩ	25			V/mV
Output Voltage Swing	V <sub>S</sub> = ±15V, R <sub>L</sub> = 10 kΩ	±13	±14		V
Input Voltage Range	V <sub>S</sub> = ±15V	±13.5			V
Common Mode Rejection Ratio		85	100		dB
Supply Voltage Rejection Ratio		80	96		dB

**NOTES**

- The maximum junction temperature of the LM108 is 150°C, while that of the LM208 is 100°C. For operating at elevated temperatures, devices in the TO-5 package must be derated based on a thermal resistance of 150°C/W, junction to ambient, or 45°C/W, junction to case. For the flat package, the derating is based on a thermal resistance of 185°C/W when mounted on a 1/16-inch-thick epoxy glass board with ten, 0.03-inch-wide, 2-ounce copper conductors. The thermal resistance of the dual-in-line package is 100°C/W, junction to ambient.
- The inputs are shunted with back-to-back diodes for overvoltage protection. Therefore, excessive current will flow if a differential input voltage in excess of 1V is applied between the inputs unless some limiting resistance is used.
- For supply voltages less than ±15V, the absolute maximum input voltage is equal to the supply voltage.
- These specifications apply for ±5V ≤ V<sub>S</sub> ≤ ±20V and -55°C ≤ T<sub>A</sub> ≤ 125°C, unless otherwise specified. With the LM208, however, all temperature specifications are limited to -25°C ≤ T<sub>A</sub> ≤ 85°C.
- The LM108 has a guaranteed offset voltage less than 2.0 mV at 25°C and 3.0 mV for -55°C ≤ T<sub>A</sub> ≤ 125°C and V<sub>S</sub> = ±15V. The average temperature coefficient of input offset voltage is guaranteed to be less than 15 μV/°C for these same conditions.

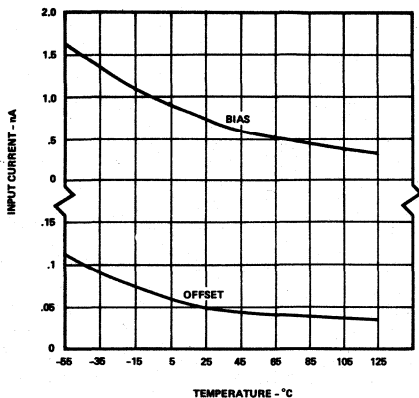
SCHEMATIC DIAGRAM



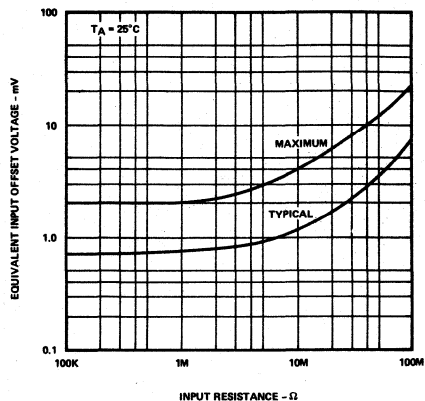
NOTE: Pin numbers for T Package.

TYPICAL CHARACTERISTICS

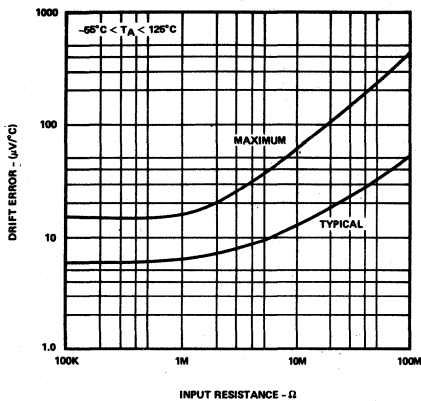
INPUT CURRENTS



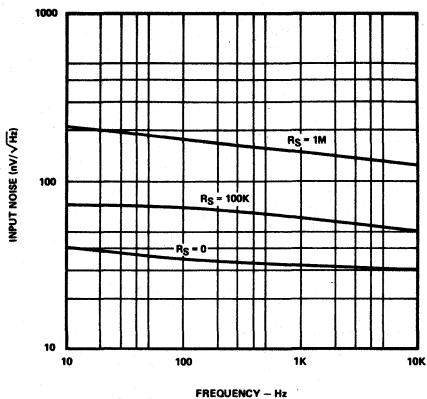
OFFSET ERROR



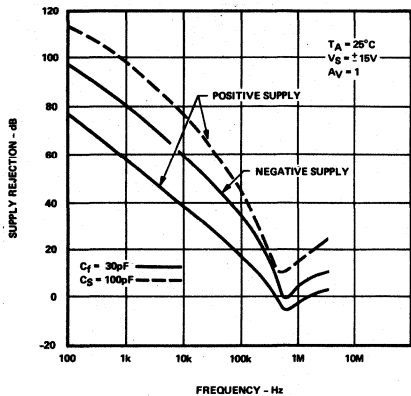
DRIFT ERROR



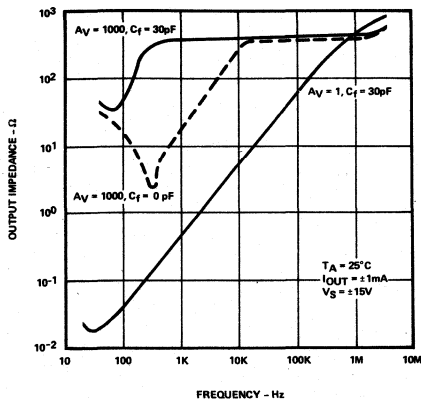
INPUT NOISE VOLTAGE



POWER SUPPLY REJECTION

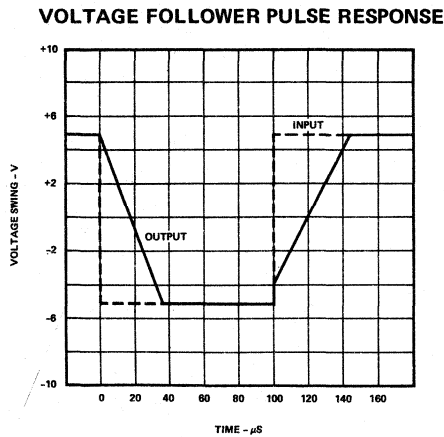
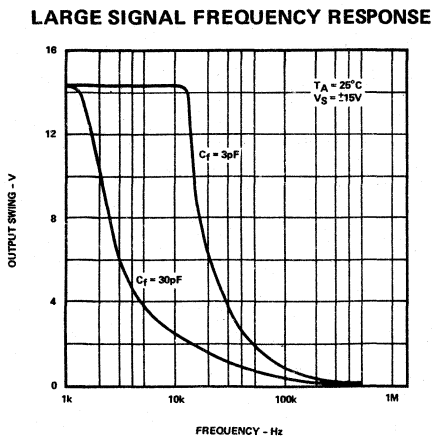
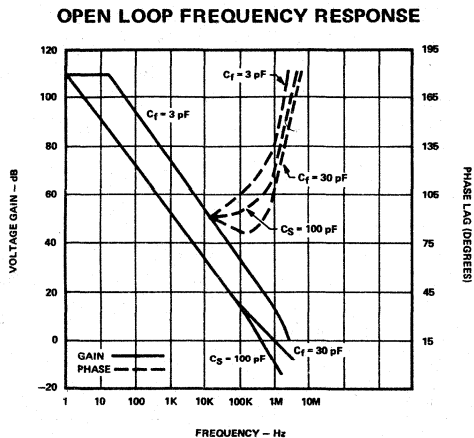
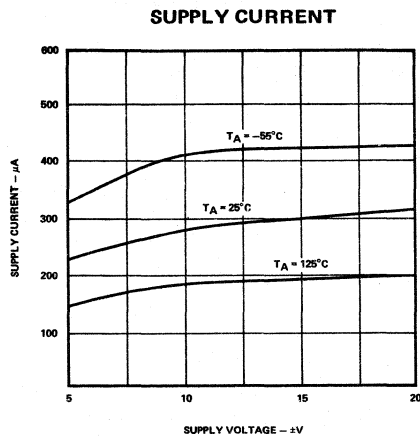
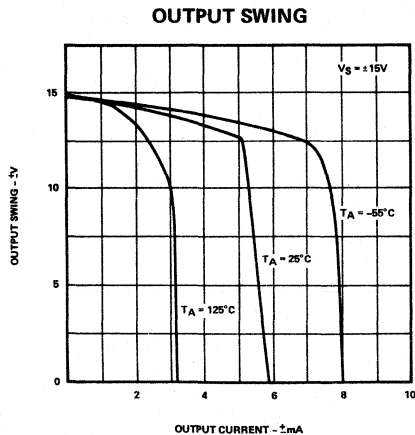
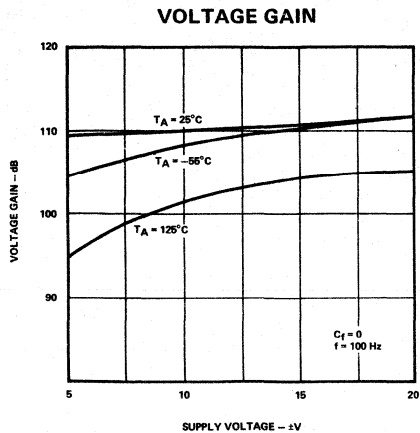


CLOSED LOOP OUTPUT IMPEDANCE





TYPICAL CHARACTERISTICS (Cont'd)



#### DESCRIPTION

The LM109 and LM309 are complete 5 volt regulators fabricated on a single silicon chip. These regulators are designed for local "on card" regulation to eliminate many of the noise and ground loop problems associated with single-point regulation. They employ internal current limiting, thermal shutdown, and safe-area compensation which makes the circuitry essentially blow-out proof. If adequate heat sinking is provided, the devices can deliver output currents in excess of 200mA from the TO-5 package, and 1A from the TO-3 package. In addition to their use as fixed 5 volt regulators, these devices may be used with external components to obtain adjustable output levels. They may also be used as the power pass element in precision regulators.

#### FEATURES

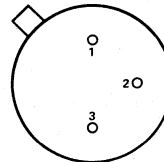
- OUTPUT CURRENTS IN EXCESS OF 1 amp
- INTERNAL THERMAL OVERLOAD PROTECTION
- INTERNAL CURRENT LIMITING
- NO EXTERNAL COMPONENTS REQUIRED

#### ABSOLUTE MAXIMUM RATINGS

Input Voltage	35V
Power Dissipation	Internally Limited
Operating Junction Temperature Range	
LM109	-55°C to 150°C
LM309	0°C to 125°C
Storage Temperature Range	-65°C to 150°C
Lead Temperature (Soldering, 10 sec)	300°C

#### PIN CONFIGURATIONS (BOTTOM VIEW)

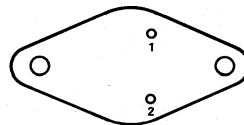
##### DB PACKAGE



1. Input
2. Output
3. Ground

ORDER PART NOS. LM109H/LM209H/LM309H

##### DA PACKAGE

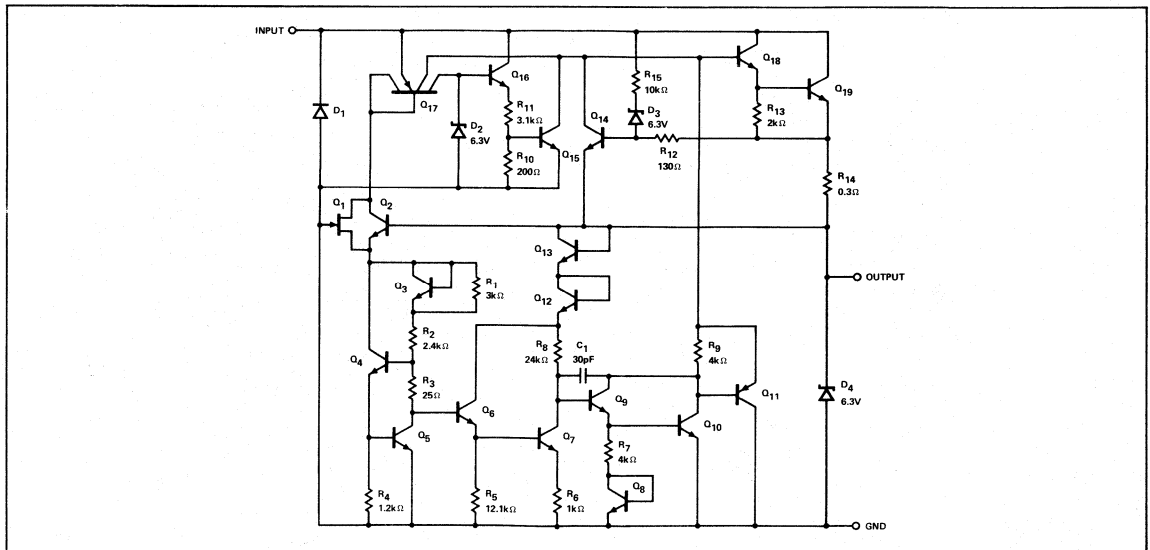


1. Input
2. Output

Case is connected to ground.

ORDER PART NOS. LM109K/LM209K/LM309K

#### EQUIVALENT CIRCUIT



ELECTRICAL CHARACTERISTICS (Note 1)

PARAMETER	CONDITIONS	LM109			LM309			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Output Voltage	$T_j = 25^\circ\text{C}$	4.7	5.05	5.3	4.8	5.05	5.2	V
Line Regulation	$T_j = 25^\circ\text{C}$ $7\text{V} \leq V_{\text{IN}} \leq 25\text{V}$		4	50		4	50	mV
Load Regulation	$T_j = 25^\circ\text{C}$							
TO-5	$5\text{mA} \leq I_{\text{OUT}} \leq 0.5\text{A}$		20	50		20	50	mV
TO-3	$5\text{mA} \leq I_{\text{OUT}} \leq 1.5\text{A}$		50	100		50	100	mV
Output Voltage	$7\text{V} \leq V_{\text{IN}} \leq 25\text{V}$ $5\text{mA} \leq I_{\text{OUT}} \leq I_{\text{max}}$ $P < P_{\text{max}}$	4.6		5.4	4.75		5.25	V
Quiescent Current	$7\text{V} \leq V_{\text{IN}} \leq 25\text{V}$		5.2	10		5.2	10	mA
Quiescent Current Change	$7\text{V} \leq V_{\text{IN}} \leq 25\text{V}$			0.5			0.5	mA
	$5\text{mA} \leq I_{\text{OUT}} \leq I_{\text{max}}$			0.8			0.8	mA
Output Noise Voltage	$T_A = 25^\circ\text{C}$ $10\text{Hz} \leq f \leq 100\text{kHz}$		40			40		$\mu\text{V}$
Long Term Stability				10			20	mV
Thermal Resistance								
Junction to Case (Note 2)								$^\circ\text{C/W}$
TO-5			15			15		$^\circ\text{C/W}$
TO-3			3			3		$^\circ\text{C/W}$

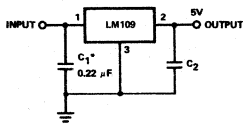
NOTES:

1. Unless otherwise specified, these specifications apply for  $-55^\circ\text{C} \leq T_j \leq 150^\circ\text{C}$  for the 5109 or  $0^\circ\text{C} \leq T_j \leq 125^\circ\text{C}$  for the 5309,  $V_{\text{IN}} = 10\text{V}$  and  $I_{\text{OUT}} = 0.1\text{A}$  for the TO-5 package or  $I_{\text{OUT}} = 0.5\text{A}$  for the TO-3 package. For the TO-5 package,  $I_{\text{max}} = 0.2\text{A}$  and  $P_{\text{max}} = 2.0\text{W}$ . For the TO-3 package,  $I_{\text{max}} = 1.0\text{A}$  and  $P_{\text{max}} = 20\text{W}$ .

2. Without a heat sink, the thermal resistance of the TO-5 package is about  $150^\circ\text{C/W}$ , while that of the TO-3 package is approximately  $35^\circ\text{C/W}$ . With a heat sink, the effective thermal resistance can only approach the values specified, depending on the efficiency of the sink.

TYPICAL APPLICATIONS

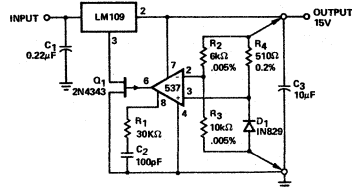
FIXED 5V REGULATOR



NOTES: \*Required if regulator is located an appreciable distance from power supply filter.

†Although no output capacitor is needed for stability, it does improve transient response.

PRECISION VOLTAGE REGULATOR

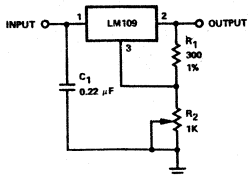


NOTES: \*Regulation better than 0.01% load, line and temperature, can be obtained.

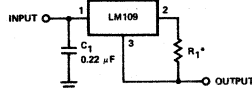
†Determines zener current. May be adjusted to minimize thermal drift.

‡Solid tantalum.

ADJUSTABLE OUTPUT REGULATOR



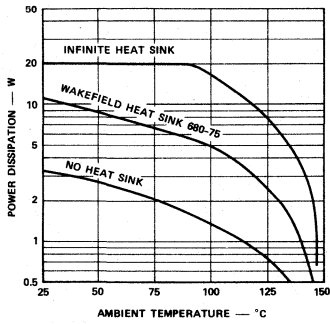
CURRENT REGULATOR



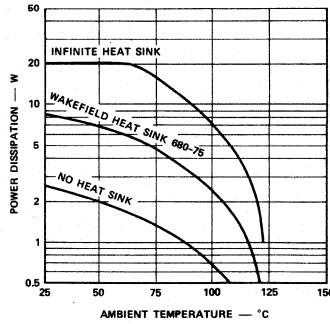
NOTES: \*Determines output current.

TYPICAL CHARACTERISTIC CURVES

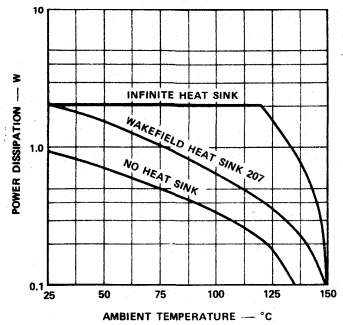
MAXIMUM AVERAGE POWER DISSIPATION LM109/LM209 (TO-3)



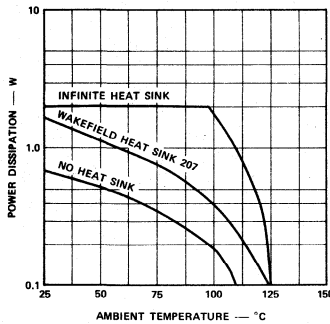
MAXIMUM AVERAGE POWER DISSIPATION LM309 (TO-3)



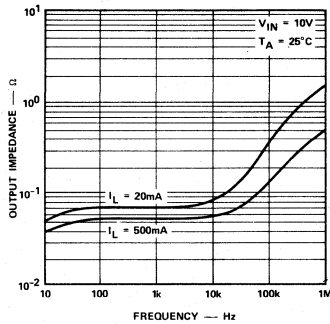
MAXIMUM AVERAGE POWER DISSIPATION LM109/LM209 (TO-5)



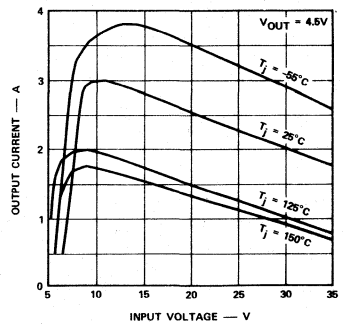
MAXIMUM AVERAGE POWER DISSIPATION LM309 (TO-5)



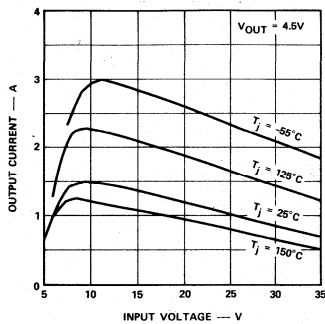
OUTPUT IMPEDANCE



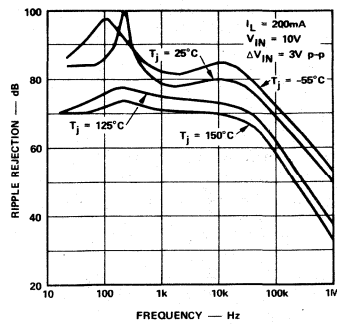
PEAK OUTPUT CURRENT K PACKAGE (TO-3)



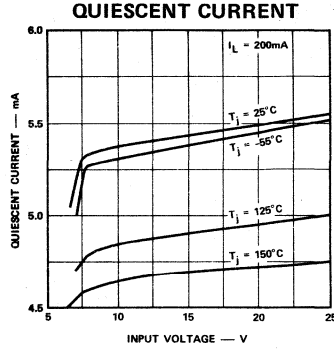
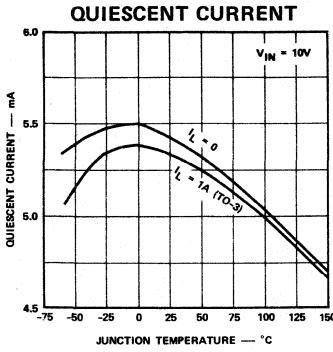
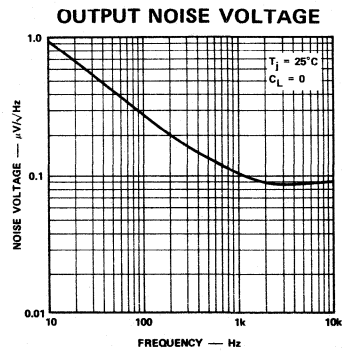
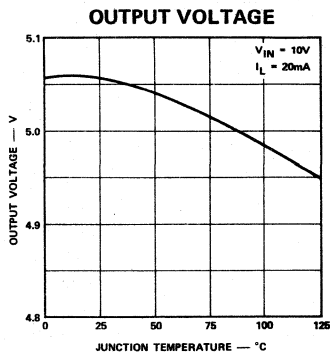
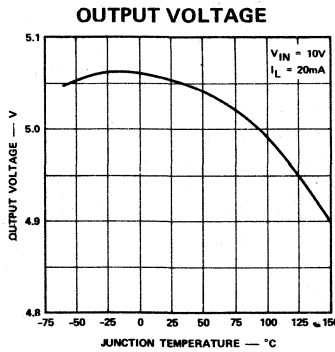
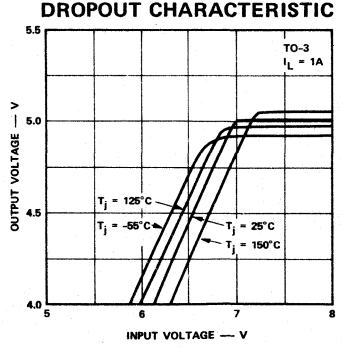
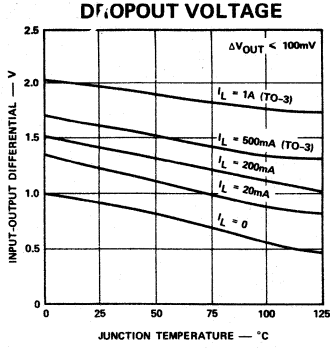
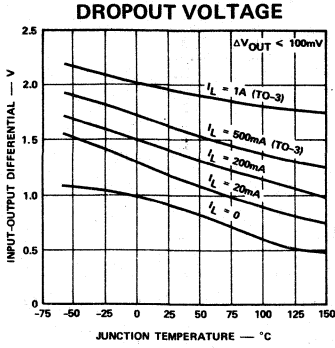
PEAK OUTPUT CURRENT H PACKAGE (TO-5)



RIPPLE REJECTION



TYPICAL CHARACTERISTIC CURVES (Cont'd.)



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The LM111 and LM211 are voltage comparators that have input currents nearly a thousand times lower than devices like the  $\mu A710$ . They are also designed to operate over a wider range of supply voltages: from standard  $\pm 15V$  op amp supplies down to the single 5V supply used for IC logic. Their output is compatible with RTL, DTL and TTL as well as MOS circuits. Further, they can drive lamps or relays, switching voltages up to 50V at currents as high as 50mA.

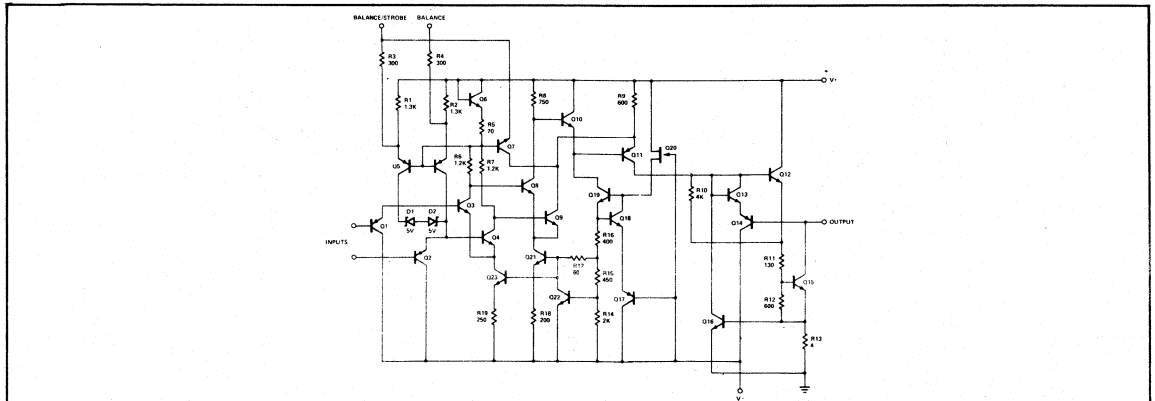
Both the inputs and the outputs of the LM111 or the LM211 can be isolated from system ground, and the output can drive loads referred to ground, the positive supply or the negative supply. Offset balancing and strobe capability are provided and outputs can be wire OR'ed. Although slower than the  $\mu A710$  (200ns response time vs 40ns) the devices are also much less prone to spurious oscillations. The LM111 has the same pin configuration as the  $\mu A710$ .

The LM211 is identical to the LM111, except that its performance is specified over a  $-25^{\circ}C$  to  $85^{\circ}C$  temperature range instead of  $-55^{\circ}C$  to  $125^{\circ}C$ .

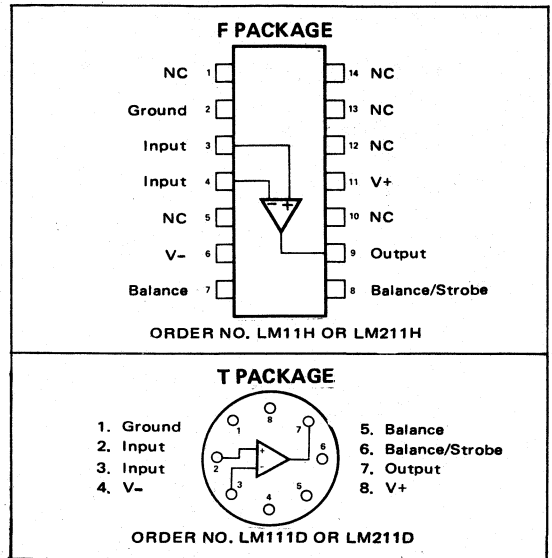
### FEATURES

- OPERATES FROM SINGLE 5V SUPPLY
- MAXIMUM INPUT CURRENT: 150nA
- MAXIMUM OFFSET CURRENT: 20nA
- DIFFERENTIAL INPUT VOLTAGE RANGE:  $\pm 30V$
- POWER CONSUMPTION: 135mW AT  $\pm 15V$
- HIGH SENSITIVITY – 200V/mV

### CIRCUIT SCHEMATIC



### PIN CONFIGURATIONS (Top View)



### ABSOLUTE MAXIMUM RATINGS

Total Supply Voltage	36V
Output to Negative Supply Voltage	50V
Ground to Negative Supply Voltage	30V
Differential Input Voltage	$\pm 30V$
Input Voltage (Note 1)	$\pm 15V$
Power Dissipation	500mW
Output Short Circuit Duration	10 sec
Operating Temperature Range LM111	$-55^{\circ}C$ to $125^{\circ}C$
LM211	$-25^{\circ}C$ to $85^{\circ}C$
Storage Temperature Range	$-65^{\circ}C$ to $150^{\circ}C$
Lead Temperature (Soldering, 10 sec)	$300^{\circ}C$

ELECTRICAL CHARACTERISTICS (Note 2)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage (Note 3)	$T_A = 25^\circ\text{C}$ , $R_S \leq 50\text{k}$		0.7	3.0	mV
Input Offset Current (Note 3)	$T_A = 25^\circ\text{C}$		4.0	10	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		60	100	nA
Voltage Gain	$T_A = 25^\circ\text{C}$		200		V/mV
Response Time (Note 4)	$T_A = 25^\circ\text{C}$		200		ns
Saturation Voltage	$V_{IN} \leq -5\text{mV}$ , $I_{OUT} = 50\text{mA}$ $T_A = 25^\circ\text{C}$		0.75	1.5	V
Strobe On Current	$T_A = 25^\circ\text{C}$		3.0		mA
Output Leakage Current	$V_{IN} \geq 5\text{mV}$ , $V_{OUT} = 35\text{V}$ $T_A = 25^\circ\text{C}$		0.2	10	nA
Input Offset Voltage (Note 3)	$R_S \leq 50\text{k}$			4.0	mV
Input Offset Current (Note 3)				20	nA
Input Bias Current				150	nA
Input Voltage Range			$\pm 14$		V
Saturation Voltage	$V^+ \geq 4.5\text{V}$ , $V^- = 0$ $V_{IN} \leq -6\text{mV}$ , $I_{SINK} \leq 8\text{mA}$		0.23	0.4	V
Output Leakage Current	$V_{IN} \geq 5\text{mV}$ , $V_{OUT} = 35\text{V}$		0.1	0.5	$\mu\text{A}$
Positive Supply Current	$T_A = 25^\circ\text{C}$		5.1	6.0	mA
Negative Supply Current	$T_A = 25^\circ\text{C}$		4.1	5.0	mA

NOTES

1. This rating applies for  $\pm 15\text{V}$  supplies. The positive input voltage limit is 30V above the negative supply. The negative input voltage limit is equal to the negative supply voltage or 30V below the positive supply, whichever is less.
2. These specifications apply for  $V_S = \pm 15\text{V}$  and  $-55^\circ\text{C} \leq T_A \leq 125^\circ\text{C}$ , unless otherwise stated. With the LM211, however, all temperature specifications are limited to  $-25^\circ\text{C} \leq T_A \leq 85^\circ\text{C}$ . The offset voltage, offset current and bias current specifications apply for any supply voltage from a single 5V supply up to  $\pm 15\text{V}$  supplies.
3. The offset voltages and offset currents given are the maximum values required to drive the output within a volt of either supply with a 1mA load. Thus, these parameters define an error band and take into account the worst case effects of voltage gain and input impedance.
4. The response time specified (see definitions) is for a 100mV input step with 5mV overdrive.

#### DESCRIPTION

The LM119/LM219 are precision high speed dual comparators fabricated on a single monolithic chip. They are designed to operate over a wide range of supply voltages down to a single 5V logic supply and ground. Further, they have higher gain and lower input currents than devices like the  $\mu A710$ . The uncommitted collector of the output stage makes the LM119 compatible with RTL, DTL and TTL as well as capable of driving lamps and relays at currents up to 25mA.

Although designed primarily for applications requiring operation from digital logic supplies, the LM119 is fully specified for power supplies up to  $\pm 15V$ . It features faster response than the LM111 at the expense of higher power dissipation. However, the high speed, wide operating voltage range and low package count make the LM119 much more versatile than older devices like the  $\mu A711$ .

The LM219 is identical to the LM119, except that its performance is specified over a  $-25^{\circ}C$  to  $85^{\circ}C$  temperature range instead of  $-55^{\circ}C$  to  $125^{\circ}C$ .

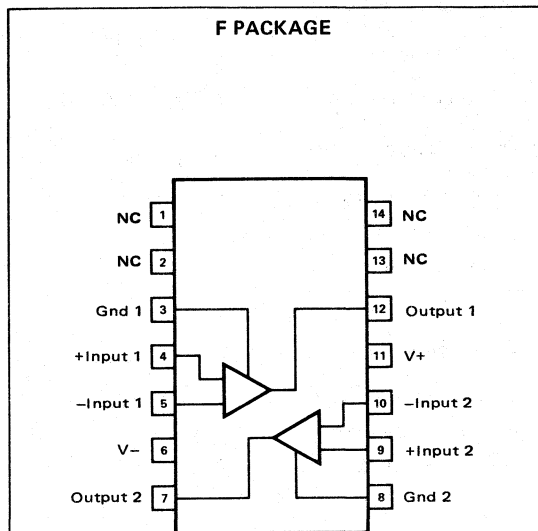
#### FEATURES

- TWO INDEPENDENT COMPARATORS
- OPERATES FROM A SINGLE 5V SUPPLY
- TYPICALLY 80ns RESPONSE TIME AT  $\pm 15V$
- MINIMUM FAN-OUT OF 2 (EACH SIDE)
- MAXIMUM INPUT CURRENT OF  $1\mu A$  OVER TEMPERATURE
- INPUTS AND OUTPUTS CAN BE ISOLATED FROM SYSTEM GROUND
- HIGH COMMON MODE SLEW RATE

#### ABSOLUTE MAXIMUM RATINGS

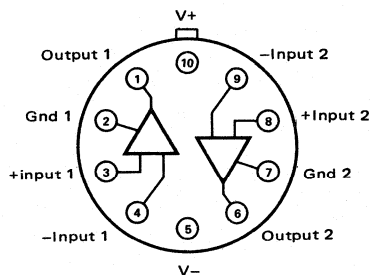
Total Supply Voltage	36V
Output to Negative Supply Voltage	36V
Ground to Negative Supply Voltage	25V
Ground to Positive Supply Voltage	18V
Differential Input Voltage	$\pm 5V$
Input Voltage (Note 1)	$\pm 15V$
Power Dissipation (Note 2)	500mW
Output Short Circuit Duration	10 sec
Operating Temperature Range LM119	$-55^{\circ}C$ to $125^{\circ}C$
LM219	$-25^{\circ}C$ to $85^{\circ}C$
Storage Temperature Range	$-65^{\circ}C$ to $150^{\circ}C$
Lead Temperature (Soldering, 10 sec)	$300^{\circ}C$

#### PIN CONFIGURATIONS (Top View)



ORDER NO. LM119D OR LM219D

#### K PACKAGE



ORDER NO. LM119H OR LM219H

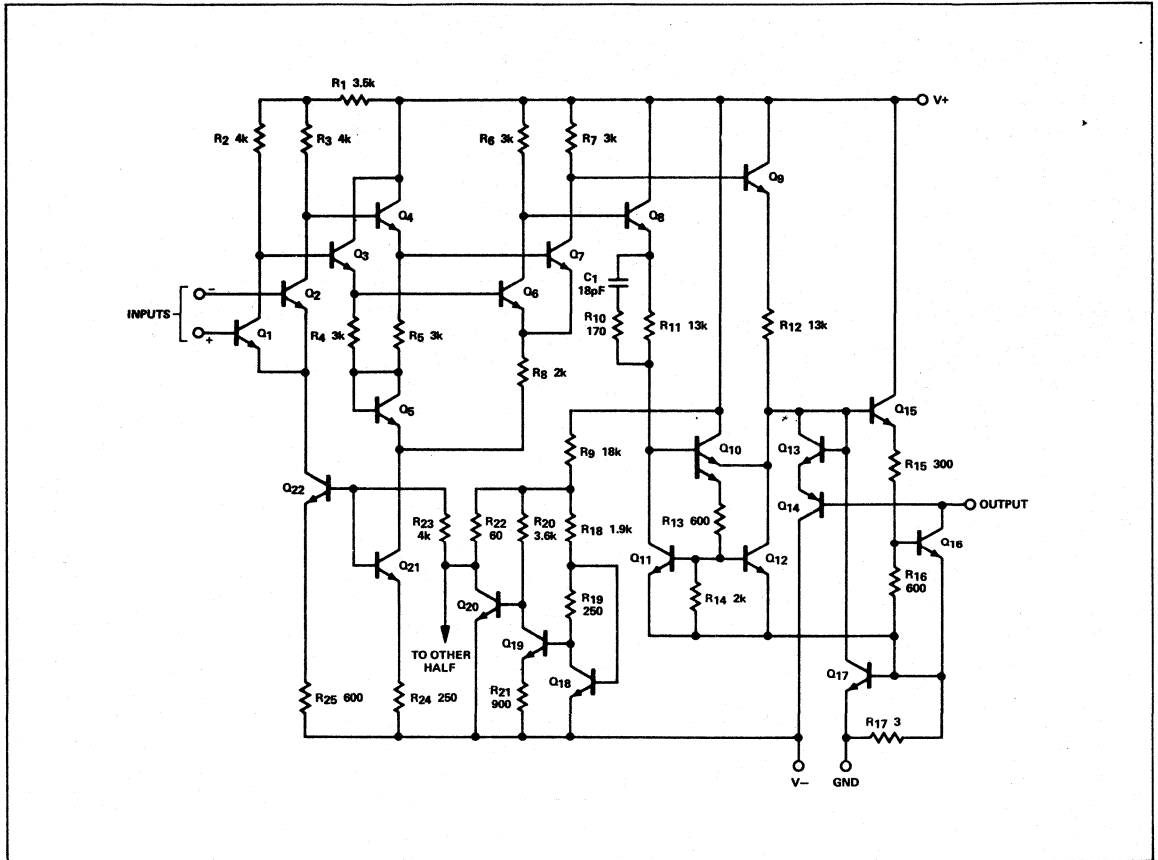


**ELECTRICAL CHARACTERISTICS** (Note 2)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage (Note 3)	$T_A = 25^\circ\text{C}$ , $R_S \leq 5k$		0.7	4.0	mV
Input Offset Current (Note 3)	$T_A = 25^\circ\text{C}$		30	75	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		150	500	nA
Voltage Gain	$T_A = 25^\circ\text{C}$	10	40		V/mV
Response Time (Note 4)	$T_A = 25^\circ\text{C}$ , $V_S = \pm 15V$		80		ns
Saturation Voltage	$V_{IN} \leq -5mV$ , $I_{OUT} = 25mA$ $T_A = 25^\circ\text{C}$		0.75	1.5	V
Output Leakage Current	$V_{IN} \geq 5mV$ , $V_{OUT} = 35V$ $T_A = 25^\circ\text{C}$		0.2	2	$\mu A$
Input Offset Voltage (Note 3)	$R_S \leq 5k$			7	mV
Input Offset Current (Note 3)				100	nA
Input Bias Current				1000	nA
Input Voltage Range	$V_S = \pm 15V$ $V^+ = 5V$ , $V^- = 0$	1	$\pm 13$	3	V
Saturation Voltage	$V^+ \geq 4.5V$ , $V^- = 0$ $V_{IN} \leq -6mV$ , $I_{SINK} \leq 3.2mA$ $T_A \geq 0^\circ\text{C}$ $T_A \leq 0^\circ\text{C}$		0.23	0.4	V
Output Leakage Current	$V_{IN} \geq 5mV$ , $V_{OUT} = 35V$		1	10	$\mu A$
Differential Input Voltage				$\pm 5$	V
Positive Supply Current	$T_A = 25^\circ\text{C}$ , $V^+ = 5V$ , $V^- = 0$		4.3		mA
Positive Supply Current	$T_A = 25^\circ\text{C}$ , $V_S = \pm 15V$		8	11.5	mA
Negative Supply Current	$T_A = 25^\circ\text{C}$ , $V_S = \pm 15V$		3	4.5	mA

- NOTES
- For supply voltages less than  $\pm 15V$  the absolute maximum input voltage is equal to the supply voltage.
  - These specifications apply for  $V_S = \pm 15V$  and  $-55^\circ\text{C} \leq T_A \leq 125^\circ\text{C}$ , unless otherwise stated. With the LM219, however, all temperature specifications are limited to  $-25^\circ\text{C} \leq T_A \leq 85^\circ\text{C}$ . The offset voltage, offset current and bias current specifications apply for any supply voltage from a single 5V supply up to  $\pm 15V$  supplies.
  - The offset voltages and offset currents given are the maximum values required to drive the output within a volt of either supply with a 1mA load. Thus, these parameters define an error band and take into account the worst case effects of voltage gain and input impedance.
  - The response time specified is for a 100mV input step with 5mV overdrive.

CIRCUIT SCHEMATIC



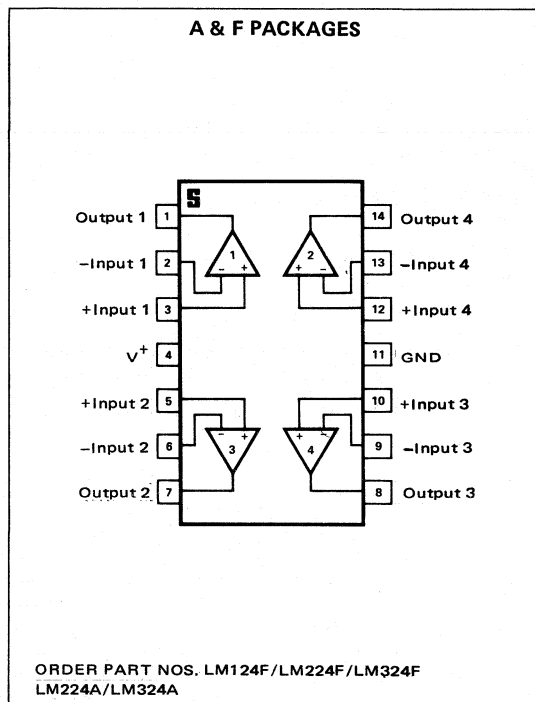
## ADVANCED INFORMATION

## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

The LM124 series consists of four independent, high gain, internally frequency compensated operational amplifiers designed specifically to operate from a single power supply over a wide range of voltages. Operation from dual power supplies is also possible and the low power supply current drain is independent of the magnitude of the power supply voltage.

### PIN CONFIGURATION (Top View)



### FEATURES

- INTERNALLY FREQUENCY COMPENSATED FOR UNITY GAIN
- LARGE DC VOLTAGE GAIN 100 dB
- WIDE BANDWIDTH (UNITY GAIN) 1 MHz  
(TEMPERATURE COMPENSATED)
- WIDE POWER SUPPLY RANGE:
  - SINGLE SUPPLY  $3V_{DC}$  to  $30V_{DC}$
  - OR DUAL SUPPLIES  $\pm 1.5V_{DC}$  to  $\pm 15V_{DC}$
- VERY LOW SUPPLY CURRENT DRAIN ( $800\mu A$ ) — ESSENTIALLY INDEPENDENT OF SUPPLY VOLTAGE ( $1\text{ mW/op amp at } +5V_{DC}$ )
- LOW INPUT BIASING CURRENT  $45\text{ nA}_{DC}$   
(TEMPERATURE COMPENSATED)
- LOW INPUT OFFSET VOLTAGE  $2\text{ mV}_{DC}$   
AND OFFSET CURRENT  $5\text{ nA}_{DC}$
- DIFFERENTIAL INPUT VOLTAGE RANGE EQUAL TO THE POWER SUPPLY VOLTAGE
- LARGE OUTPUT VOLTAGE  $0V_{DC}$  to  $V^+$   $-1.5V_{DC}$   
SWING

### UNIQUE FEATURES

IN THE LINEAR MODE THE INPUT COMMON-MODE VOLTAGE RANGE INCLUDES GROUND AND THE OUTPUT VOLTAGE CAN ALSO SWING TO GROUND, EVEN THOUGH OPERATED FROM ONLY A SINGLE POWER SUPPLY VOLTAGE.

THE UNITY GAIN CROSS FREQUENCY IS TEMPERATURE COMPENSATED.

THE INPUT BIAS CURRENT IS ALSO TEMPERATURE COMPENSATED.

### ABSOLUTE MAXIMUM RATINGS

Supply Voltage, $V^+$	$32 V_{DC}$ or $\pm 16 V_{DC}$
Differential Input Voltage	$32 V_{DC}$
Input Voltage	$-0.3 V_{DC}$ to $+32 V_{DC}$
Power Dissipation (Note 1)	
Molded DIP (LM224A, LM324A)	570 mW
Cavity DIP (LM124F, LM224F, & LM324F)	900 mW
Output Short-Circuit to GND (Note 2)	Continuous
$V^+ \leq 15 V_{DC}$ and $T_A = 25^\circ C$	
Operating Temperature Range	
LM324	$0^\circ C$ to $+70^\circ C$
LM224	$-25^\circ C$ to $+85^\circ C$
LM124	$-55^\circ C$ to $+125^\circ C$
Storage Temperature Range	$-65^\circ C$ to $+150^\circ C$
Lead Temperature (Soldering, 10 sec)	$300^\circ C$

# SIGNETICS QUAD OPERATIONAL AMPLIFIER ■ LM124/LM224/LM324

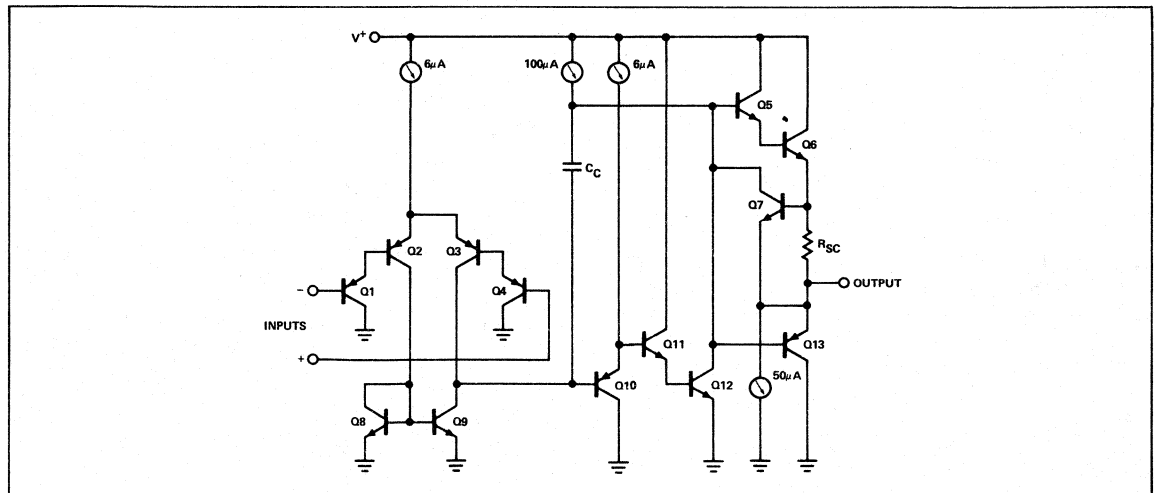
ELECTRICAL CHARACTERISTICS ( $V^+ = +5 V_{DC}$  and  $T_A = 25^\circ C$  unless otherwise noted)

PARAMETER	CONDITIONS	LM124			LM224, LM324			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Input Offset Voltage	$R_s = 0\Omega$		2	5		2	7	$mV_{DC}$
Input Bias Current (Note 3)	$I_{IN(+)}$ or $I_{IN(-)}$		45	300		45	500	$nA_{DC}$
Input Offset Current	$I_{IN(+)}$ or $I_{IN(-)}$		$\pm 3$	$\pm 30$		$\pm 5$	$\pm 50$	$nA_{DC}$
Input Common-Mode Voltage Range (Note 4)		0		$V^+ - 1.5$	0		$V^+ - 1.5$	$V_{DC}$
Supply Current	$R_L = \infty$ On All Op Amps		0.8	2		0.8	2	$mA_{DC}$
Large Signal Voltage Gain	$R_L \geq 2 k\Omega$		100			100		$V/mV$
Output Voltage Swing	$R_L = 2 k\Omega$	0		$V^+ - 1.5$	0		$V^+ - 1.5$	$V_{DC}$
Common Mode Rejection Ratio	DC		85			85		dB
Power Supply Rejection Ratio	DC		100			100		dB
Amplifier-to-Amplifier Coupling	$f = 1 \text{ kHz to } 20 \text{ kHz}$ (Input Referred)		-120			-120		dB
Output Current Source	$V_{IN}^+ = +1 V_{DC}$ ; $V_{IN}^- = 0 V_{DC}$	20	40		20	40		$mA_{DC}$
Output Current Sink	$V_{IN}^- = +1 V_{DC}$ ; $V_{IN}^+ = 0 V_{DC}$	10	20		10	20		$mA_{DC}$

## NOTES

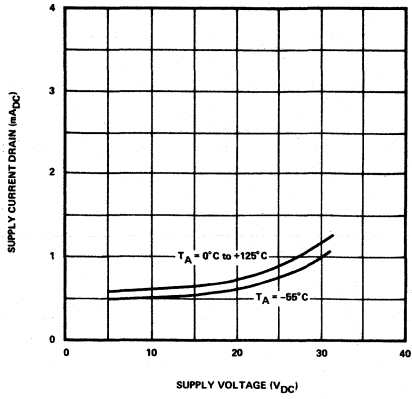
- For operating at high temperatures, the LM324 must be derated based on a  $+125^\circ C$  maximum junction temperature and a thermal resistance of  $175^\circ C/W$  which applies for the device soldered in a printed circuit board, operating in a still air ambient. The LM224 and LM124 can be derated based on a  $+150^\circ C$  maximum junction temperature.
- Short circuits from the output to  $V^+$  can cause excessive heating and eventual destruction. The maximum output current is approximately 40 mA independent of the magnitude of  $V^+$ . At values of supply voltage in excess of  $+15V_{DC}$ , continuous short-circuits can exceed the power dissipation ratings and cause eventual destruction.
- The direction of the input current is out of the IC due to the PNP input stage. This current is essentially constant, independent of the state of the output so no loading change exists on the input lines.
- The input common-mode voltage or either input signal voltage should not be allowed to go negative by more than 0.3V. The upper end of the common-mode voltage range is  $V^+ - 1.5V$ , but either or both inputs can go to  $+30V_{DC}$  without damage.

## EQUIVALENT CIRCUIT

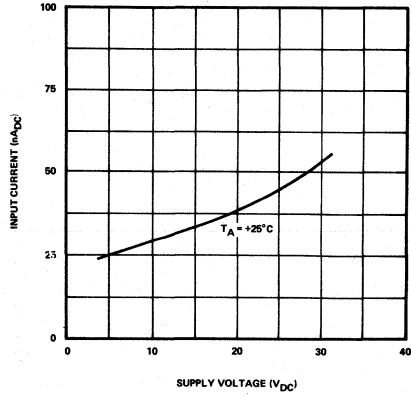


TYPICAL PERFORMANCE CURVES

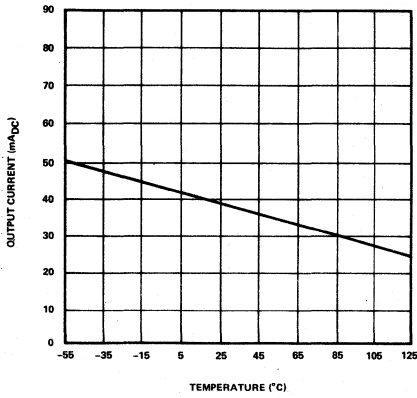
SUPPLY CURRENT



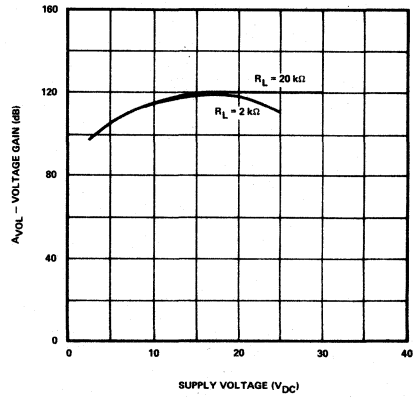
INPUT CURRENT



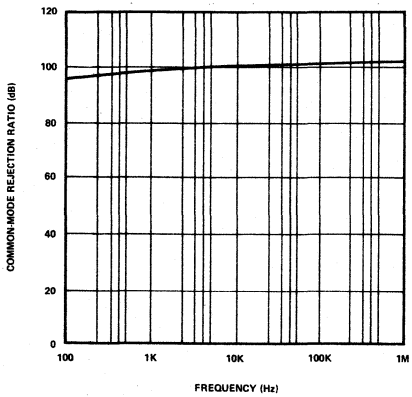
CURRENT LIMITING



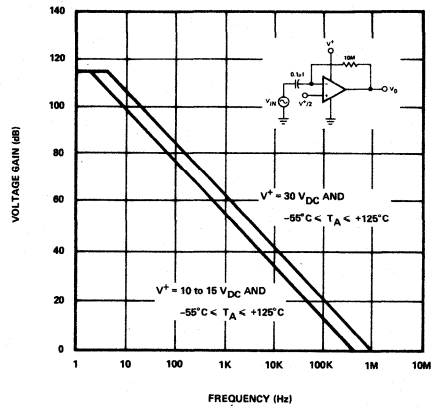
VOLTAGE GAIN



COMMON-MODE REJECTION RATIO

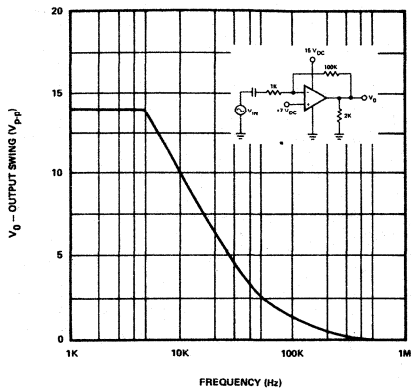


OPEN LOOP FREQUENCY RESPONSE

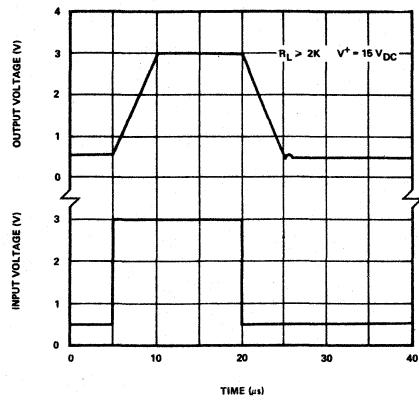


TYPICAL PERFORMANCE CURVES (Cont'd)

LARGE SIGNAL FREQUENCY RESPONSE



VOLTAGE FOLLOWER PULSE RESPONSE



### PRELIMINARY SPECIFICATION

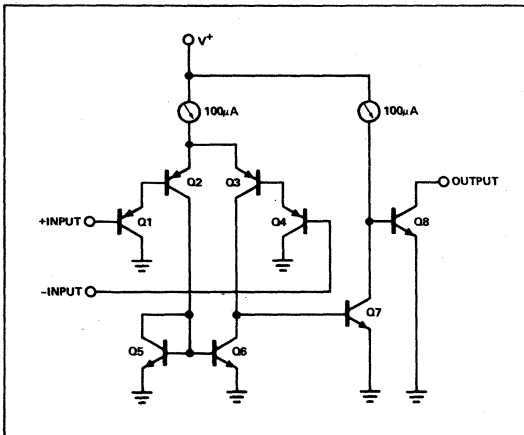
### LINEAR INTEGRATED CIRCUITS

#### DESCRIPTION

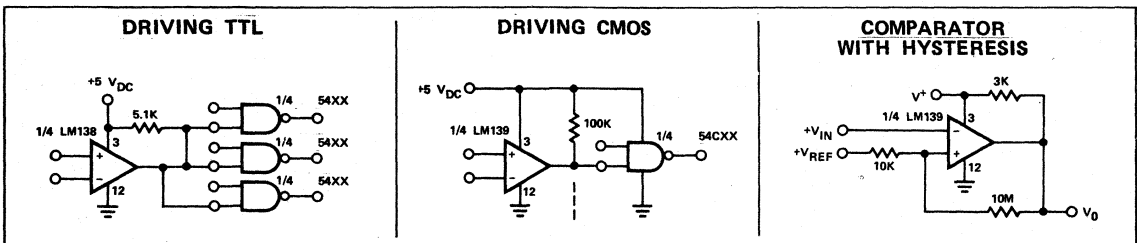
The LM139 series consists of four independent voltage comparators which were designed specifically to operate from a single power supply over a wide range of voltages. Operation from split power supplies is also possible and the low power supply current drain is independent of the magnitude of the power supply voltage. These comparators also have a unique characteristic in that the input common-mode voltage range includes ground, even though operated from a single power supply voltage.

Application areas include limit comparators, simple analog to digital converters; pulse squarewave and time delay generators; wide range VCO; MOS clock timers; multivibrators and high voltage digital logic gates. The LM139 series was designed to directly interface with TTL and CMOS. When operated from both plus and minus power supplies, the LM339 will directly interface with MOS logic — where the low power drain of the LM339 is a distinct advantage over standard comparators.

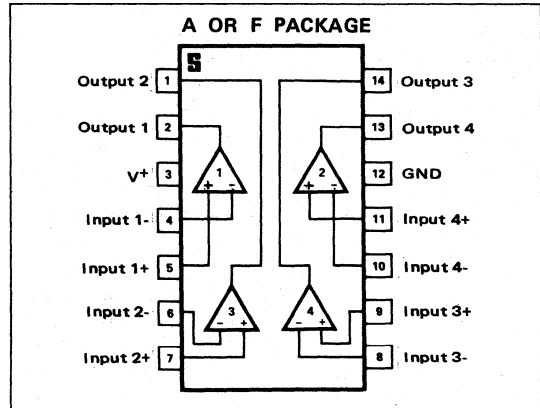
#### EQUIVALENT CIRCUIT



#### TYPICAL APPLICATIONS ( $V^+ = 5 V_{DC}$ )



#### PIN CONFIGURATION (Top View)



#### FEATURES

- **WIDE SINGLE SUPPLY VOLTAGE RANGE**  $2 V_{DC}$  to  $36 V_{DC}$   
OR DUAL SUPPLIES  $\pm 1 V_{DC}$  to  $\pm 18 V_{DC}$
- **VERY LOW SUPPLY CURRENT DRAIN (0.8 mA) — INDEPENDENT OF SUPPLY VOLTAGE (1 mW/COMPARATOR AT  $+5 V_{DC}$ )**
- **LOW INPUT BIASING CURRENT** 35 nA
- **LOW INPUT OFFSET CURRENT AND OFFSET VOLTAGE** 3 nA, 3 mV
- **INPUT COMMON-MODE VOLTAGE RANGE INCLUDES GROUND**
- **DIFFERENTIAL INPUT VOLTAGE RANGE EQUAL TO THE POWER SUPPLY VOLTAGE**
- **LOW OUTPUT SATURATION VOLTAGE** 1 mV at  $5\mu A$ , 70 mV at 1 mA
- **OUTPUT VOLTAGE COMPATIBLE WITH TTL (FAN-OUT OF 3), DTL, ECL, MOS AND CMOS LOGIC SYSTEMS**

## LINEAR INTEGRATED CIRCUITS

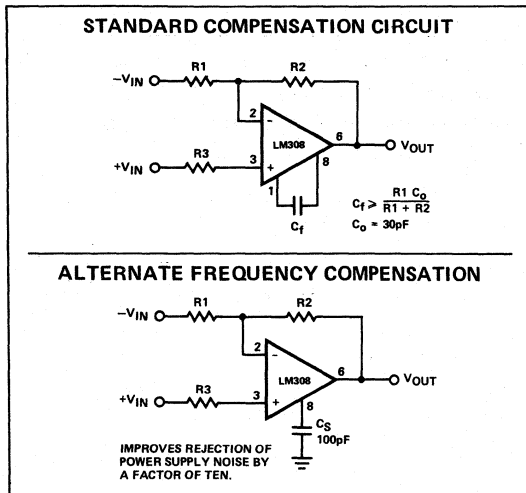
### DESCRIPTION

The LM308 is a precision operational amplifier featuring input currents nearly a thousand times lower than industry standards like the  $\mu$ A709C. In fact, its performance approaches that of high quality FET amplifiers. The circuit is directly interchangeable with the LM301A in low frequency circuits and incorporates the same protective features which make its application nearly foolproof. The device operates with supply voltages from  $\pm 2V$  to  $\pm 15V$  and has sufficient supply rejection to use unregulated supplies. Although the circuit is designed to work with the standard compensation for the LM301A, an alternate compensation scheme can be used to make it particularly insensitive to power supply noise and to make supply bypass capacitors unnecessary. Power consumption is extremely low, so the amplifiers are ideally suited for battery powered applications. The device is also well suited for use with piezoelectric, electrostatic or other capacitive transducers, in addition to low frequency active filters with small capacitor values.

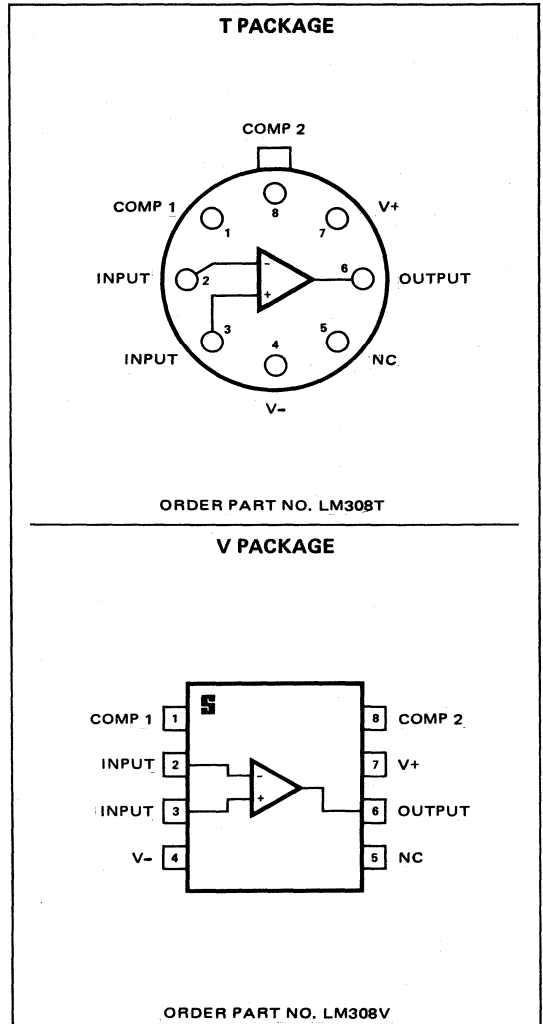
### FEATURES

- MAXIMUM INPUT BIAS CURRENT OF 7.0 nA
- OFFSET CURRENT LESS THAN 1.0 nA
- SUPPLY CURRENT OF ONLY 300  $\mu$ A, EVEN IN SATURATION
- GUARANTEED DRIFT CHARACTERISTICS
- LOW CURRENT ERROR

### COMPENSATION CIRCUITS



### PIN CONFIGURATIONS (Top View)

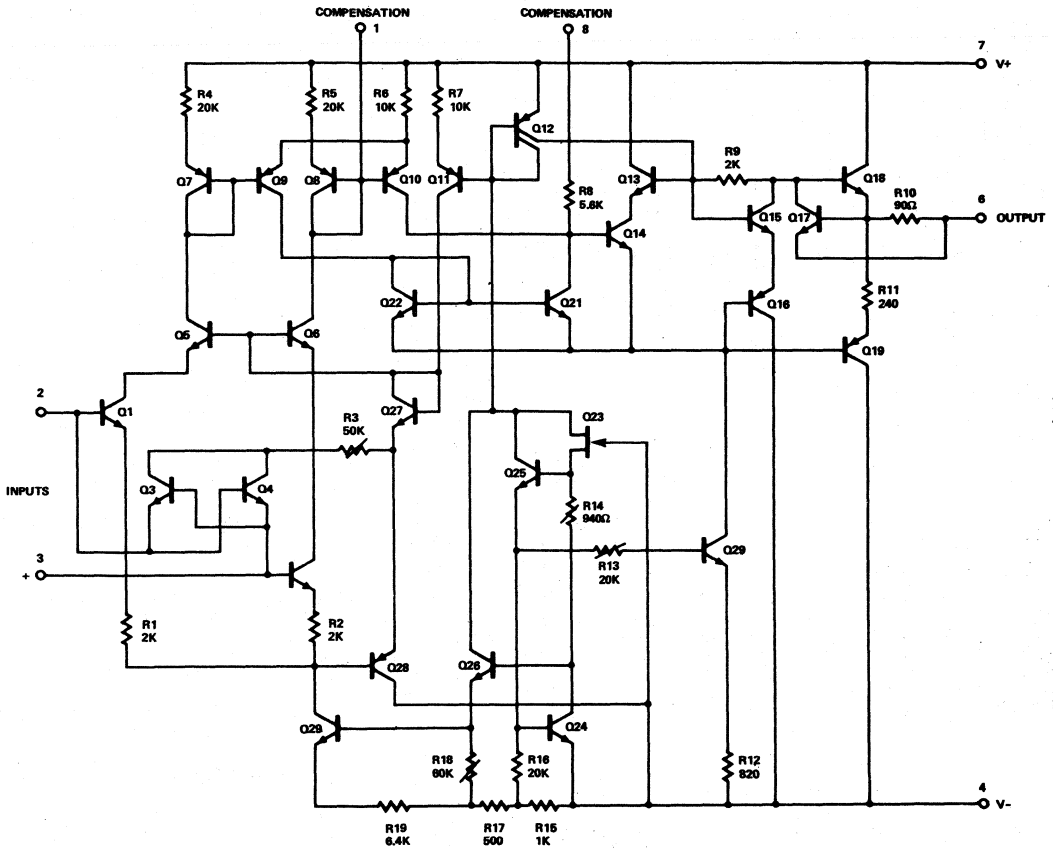


### ABSOLUTE MAXIMUM RATINGS

Supply Voltage	$\pm 18V$
Power Dissipation (Note 1)	500 mW
Differential Input Current (Note 2)	$\pm 10$ mA
Input Voltage (Note 3)	$\pm 15V$
Output Short-Circuit Duration	Indefinite
Operating Temperature Range	$0^\circ\text{C}$ to $70^\circ\text{C}$
Storage Temperature Range	$-65^\circ\text{C}$ to $150^\circ\text{C}$
Lead Temperature (Soldering, 60 sec)	300



SCHEMATIC DIAGRAM



NOTE: Pin numbers for T Package.

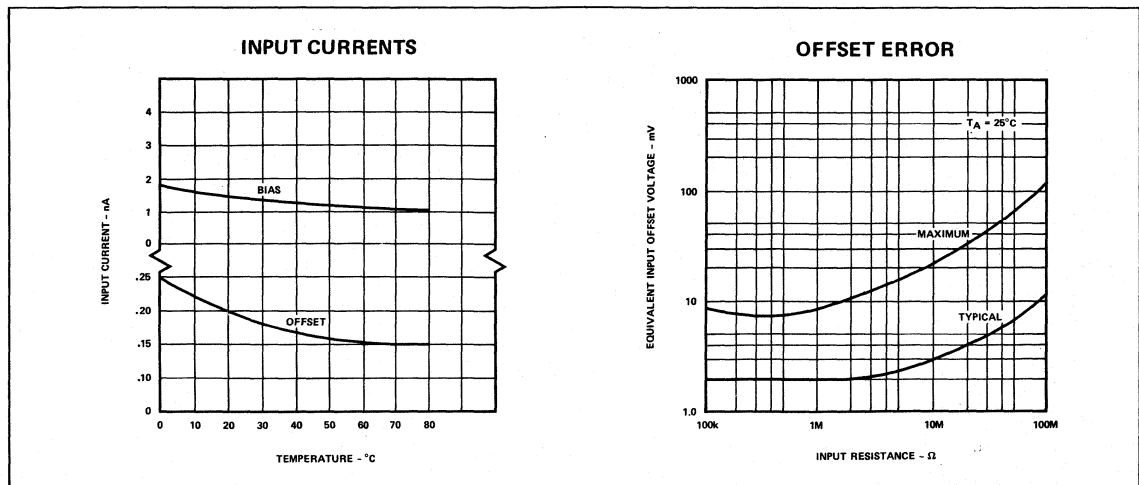
ELECTRICAL CHARACTERISTICS (Note 4)

PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage	$T_A = 25^\circ\text{C}$		2.0	7.5	mV
Input Offset Current	$T_A = 25^\circ\text{C}$		0.2	1	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		1.5	7	nA
Input Resistance	$T_A = 25^\circ\text{C}$	10	40		$\text{m}\Omega$
Supply Current	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$		0.3	0.8	mA
Large Signal Voltage Gain	$T_A = 25^\circ\text{C}, V_S = \pm 15\text{V}$ $V_{\text{OUT}} = \pm 10\text{V}, R_L \geq 10\text{ k}\Omega$	25	300		V/mV
Input Offset Voltage				10	mV
Average Temperature Coefficient of Input Offset Voltage			6.0	30	$\mu\text{V}/^\circ\text{C}$
Input Offset Current				1.5	nA
Average Temperature Coefficient of Input Offset Current			2.0	10	$\text{pA}/^\circ\text{C}$
Input Bias Current				10	nA
Large Signal Voltage Gain	$V_S = \pm 15\text{V}, V_{\text{OUT}} = \pm 10\text{V}$ $R_L \geq 10\text{ k}\Omega$	15			V/mV
Output Voltage Swing	$V_S = \pm 15\text{V}, R_L = 10\text{ k}\Omega$	$\pm 13$	$\pm 14$		V
Input Voltage Range	$V_S = \pm 15\text{V}$	$\pm 14$			V
Common Mode Rejection Ratio		80	100		dB
Supply Voltage Rejection Ratio		80	96		dB

NOTES:

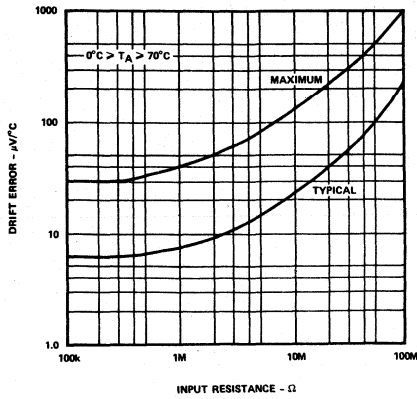
- The maximum junction temperature of the LM308 is  $85^\circ\text{C}$ . For operation at elevated temperatures, devices in the TO-5 package must be derated based on a thermal resistance of  $150^\circ\text{C}/\text{W}$ , junction to ambient, or  $45^\circ\text{C}/\text{W}$ , junction to case.  
The thermal resistance of the dual-in-line package is  $100^\circ\text{C}/\text{W}$ , junction to ambient.
- The inputs are shunted with back-to-back diodes for overvoltage protection. Therefore, excessive current will flow if a differential input voltage in excess of 1V is applied between the inputs unless some limiting resistance is used.
- For supply voltages less than  $\pm 15\text{V}$ , the absolute maximum input voltage is equal to the supply voltage.
- These specifications apply for  $\pm 5\text{V} \leq V_S \leq \pm 15\text{V}$  and  $0^\circ\text{C} \leq T_A \leq 70^\circ\text{C}$ , unless otherwise specified.

TYPICAL PERFORMANCE CHARACTERISTICS

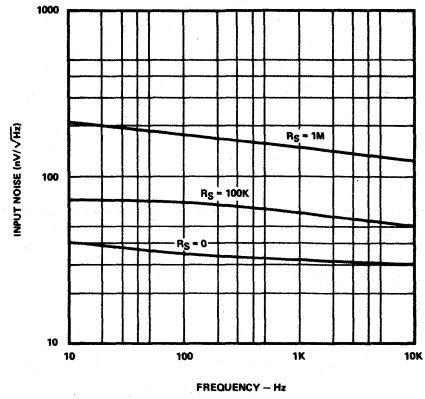


TYPICAL CHARACTERISTICS (Cont'd)

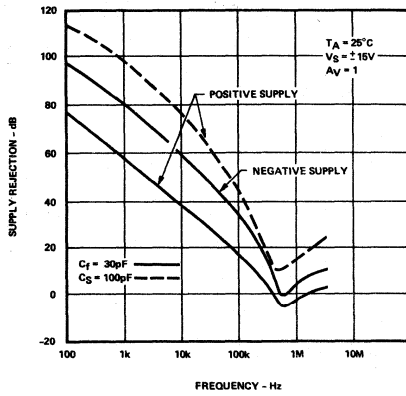
DRIFT ERROR



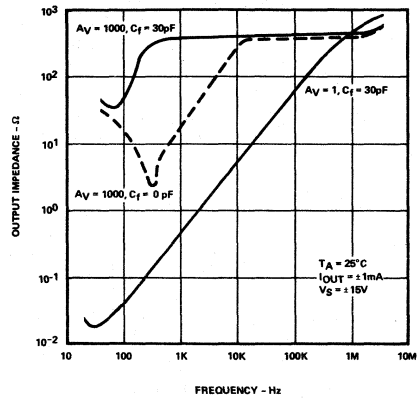
INPUT NOISE VOLTAGE



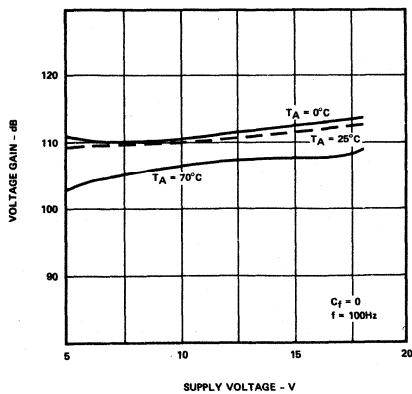
POWER SUPPLY REJECTION



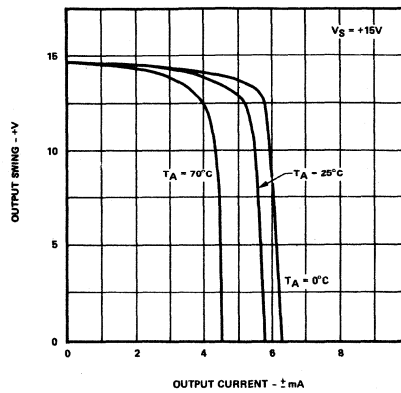
CLOSED LOOP OUTPUT IMPEDANCE



VOLTAGE GAIN

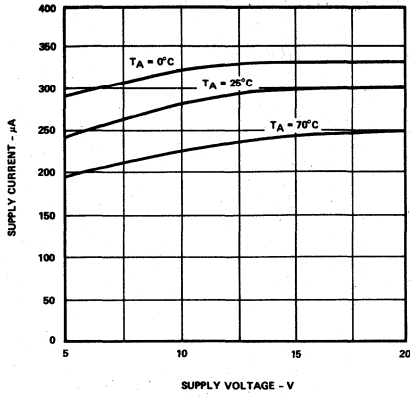


OUTPUT SWING

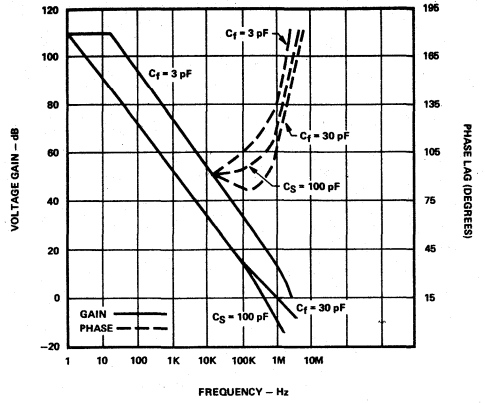


TYPICAL CHARACTERISTICS (Cont'd)

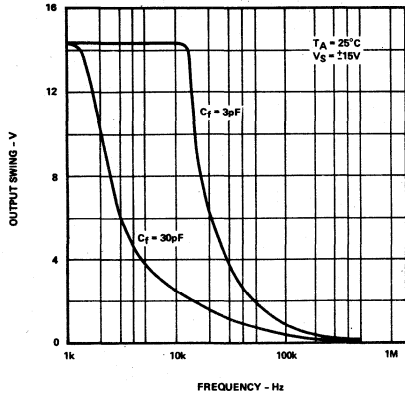
SUPPLY CURRENT



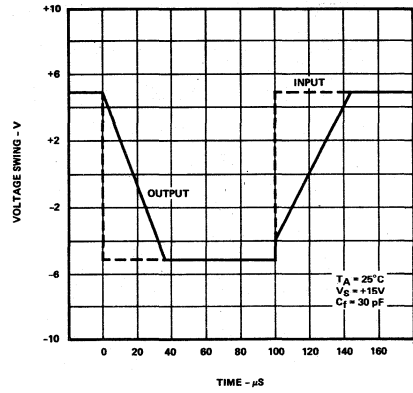
OPEN LOOP FREQUENCY RESPONSE



LARGE SIGNAL FREQUENCY RESPONSE



VOLTAGE FOLLOWER PULSE RESPONSE



## LINEAR INTEGRATED CIRCUITS

### DESCRIPTION

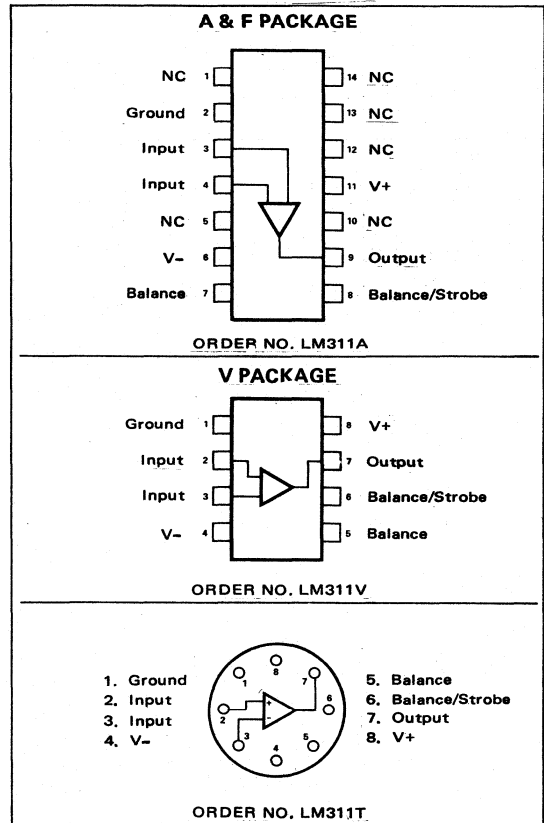
The LM311 is a voltage comparator that has input currents more than a hundred times lower than devices like the  $\mu A710C$ . It is also designed to operate over a wider range of supply voltages: from standard  $\pm 15V$  op amp supplies down to the single 5V supply used for IC logic. Its output is compatible with RTL, DTL and TTL as well as MOS circuits. Further, it can drive lamps or relays, switching voltages up to 40V at currents as high as 50 mA.

Both the input and the output of the LM311 can be isolated from system ground, and the output can drive loads referred to ground, the positive supply or the negative supply. Offset balancing and strobe capability are provided and outputs can be wire OR'ed. Although slower than the  $\mu A710C$  (200 ns response time vs 40 ns) the device is also much less prone to spurious oscillations. The LM311 has the same pin configuration as the  $\mu A710C$ .

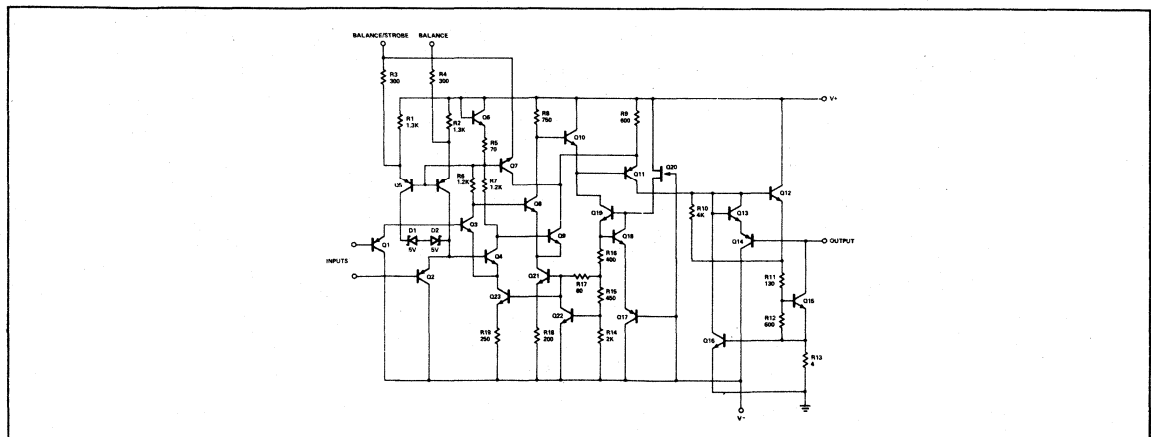
### FEATURES

- OPERATES FROM SINGLE 5V SUPPLY
- MAXIMUM INPUT CURRENT: 250 nA
- MAXIMUM OFFSET CURRENT: 50 nA
- DIFFERENTIAL INPUT VOLTAGE RANGE:  $\pm 30V$
- POWER CONSUMPTION: 135 mW AT  $\pm 15V$
- HIGH SENSITIVITY - 200 V/mV

### PIN CONFIGURATION (Top View)



### BASIC CIRCUIT SCHEMATIC



# SIGNETICS ANALOG VOLTAGE COMPARATOR ■ LM311

## ABSOLUTE MAXIMUM RATINGS

Total Supply Voltage	36V	Input Voltage (Note 1)	±15V
Output to Negative Supply Voltage	40V	Power Dissipation	500 mW
Ground to Negative Supply Voltage	30V	Output Short Circuit Duration	10 sec
Differential Input Voltage	±30V	Operating Temperature Range	0°C to 70°C
		Storage Temperature Range	-65°C to 150°C
		Lead Temperature (soldering, 10 sec)	300°C

## ELECTRICAL CHARACTERISTICS (NOTE 2)

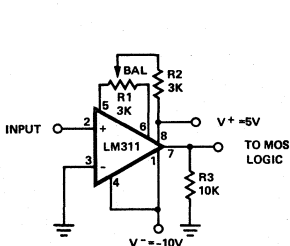
PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNITS
Input Offset Voltage (NOTE 3)	$T_A = 25^\circ\text{C}$ , $R_S \leq 50\text{K}$		2.0	7.5	mV
Input Offset Current (NOTE 3)	$T_A = 25^\circ\text{C}$		6.0	50	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		100	250	nA
Voltage Gain	$T_A = 25^\circ\text{C}$		200		V/mV
Response Time (NOTE 4)	$T_A = 25^\circ\text{C}$		200		ns
Saturation Voltage	$V_{IN} \leq -10\text{ mV}$ , $I_{OUT} = 50\text{ mA}$ $T_A = 25^\circ\text{C}$		0.75	1.5	V
Strobe On Current	$T_A = 25^\circ\text{C}$		3.0		mA
Output Leakage Current	$V_{IN} \geq 10\text{ mV}$ , $V_{OUT} = 35\text{ V}$ $T_A = 25^\circ\text{C}$		0.2	50	nA
Positive Supply Current	$T_A = 25^\circ\text{C}$		5.1	7.5	mA
Negative Supply Current	$T_A = 25^\circ\text{C}$		4.1	5.0	mA
Input Offset Voltage (NOTE 3)	$R_S \leq 50\text{K}$			10	mV
Input Offset Current (NOTE 3)				70	nA
Input Bias Current				300	nA
Input Voltage Range			±14		V
Saturation Voltage	$V^+ \geq 4.5\text{V}$ , $V^- = 0$ $V_{IN} \leq -10\text{ mV}$ , $I_{SINK} \leq 8\text{ mA}$		0.23	0.4	V

### NOTES:

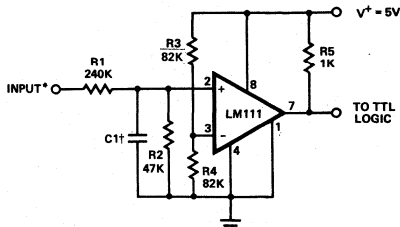
- This rating applies for ±15V supplies. The positive input voltage limit is 30V above the negative supply. The negative input voltage limit is equal to the negative supply voltage or 30V below the positive supply, whichever is less.
- These specifications apply for  $V_S = \pm 15\text{V}$  and  $0^\circ\text{C} < T_A < 70^\circ\text{C}$ , unless otherwise specified. The offset voltage, offset current and bias current specifications apply for any supply voltage from a single 5V supply up to ±15V supplies.
- The offset voltages and offset currents given are the maximum values required to drive the output within a volt of either supply with 1 mA load. Thus, these parameters define an error band and take into account the worst case effects of voltage gain and input impedance.
- The response time specified is for a 100 mV input step with 5 mV overdrive.

## TYPICAL APPLICATIONS

### ZERO CROSSING DETECTOR DRIVING MOS LOGIC



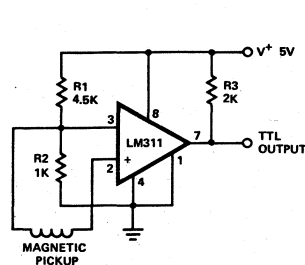
### TTL INTERFACE WITH HIGH LEVEL LOGIC



\*VALUES SHOWN ARE FOR A 0 TO 30V LOGIC SWING AND A 15V THRESHOLD.

\*MAY BE ADDED TO CONTROL SPEED AND REDUCE SUSCEPTIBILITY TO NOISE SPIKES.

### DETECTOR FOR MAGNETIC TRANSDUCER



## LINEAR INTEGRATED CIRCUITS

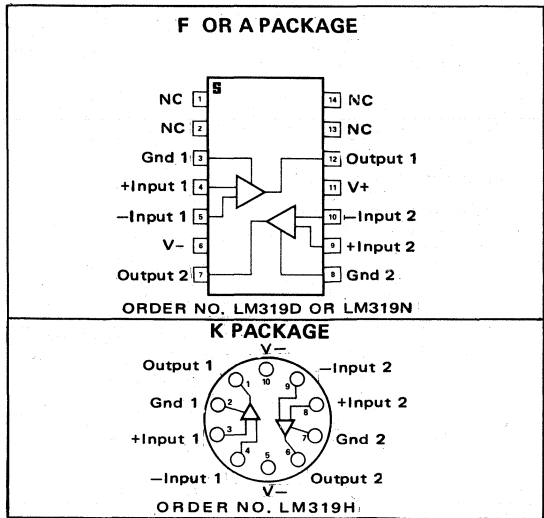
### DESCRIPTION

The LM319 is a precision high speed dual comparator fabricated on a single monolithic chip. It is designed to operate over a wide range of supply voltages down to a single 5V logic supply and ground. Further, it has higher gain and lower input currents than devices like the  $\mu A710C$ . The uncommitted collector of the output stage makes the LM319 compatible with RTL, DTL and TTL as well as capable of driving lamps and relays at currents up to 25mA.

Although designed primarily for applications requiring operation from digital logic supplies, the LM319 is fully specified for power supplies up to  $\pm 15V$ . It features faster response than the LM111 at the expense of higher power dissipation. However, the high speed, wide operating voltage range and low package count make the LM319 much more versatile than older devices like the  $\mu A711C$ .

The LM319 has its performance specified over a  $0^{\circ}C$  to  $70^{\circ}C$  temperature range.

### PIN CONFIGURATIONS (Top View)



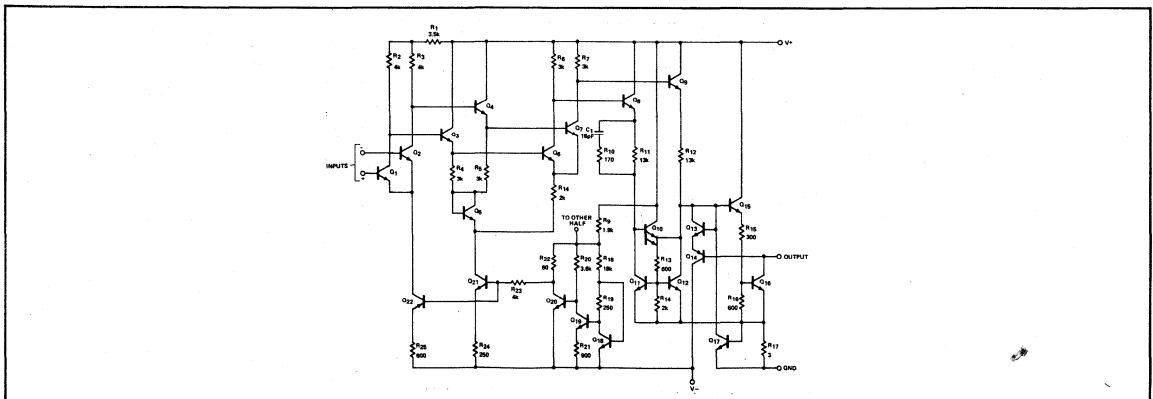
### ABSOLUTE MAXIMUM RATINGS

Total Supply Voltage	36V
Output to Negative Supply Voltage	36V
Ground to Negative Supply Voltage	25V
Ground to Positive Supply Voltage	18V
Differential Input Voltage	$\pm 5V$
Input Voltage (Note 1)	$\pm 15V$
Power Dissipation	500mW
Output Short Circuit Duration	10 sec
Operating Temperature Range LM319	$0^{\circ}C$ to $70^{\circ}C$
Storage Temperature Range	$-65^{\circ}C$ to $150^{\circ}C$
Lead Temperature (Soldering, 10 sec)	$300^{\circ}C$

### FEATURES

- TWO INDEPENDENT COMPARATORS
- OPERATES FROM A SINGLE 5V SUPPLY
- TYPICALLY 80ns RESPONSE TIME AT  $\pm 15V$
- MINIMUM FAN-OUT OF 2 (EACH SIDE)
- MAXIMUM INPUT CURRENT OF  $1\mu A$
- INPUTS AND OUTPUTS CAN BE ISOLATED FROM SYSTEM GROUND
- HIGH COMMON MODE SLEW RATE

### BASIC CIRCUIT SCHEMATIC



# SIGNETICS DUAL VOLTAGE COMPARATOR ■ LM319

## ELECTRICAL CHARACTERISTICS (Note 2)

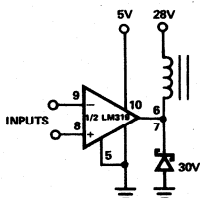
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
Input Offset Voltage (Note 3)	$T_A = 25^\circ\text{C}$ , $R_S \leq 5k$		2.0	8.0	mV
Input Offset Current (Note 3)	$T_A = 25^\circ\text{C}$		80	200	nA
Input Bias Current	$T_A = 25^\circ\text{C}$		250	1000	nA
Voltage Gain	$T_A = 25^\circ\text{C}$	8	40		V/mV
Response Time (Note 4)	$T_A = 25^\circ\text{C}$ , $V_S = \pm 15\text{V}$		80		ns
Saturation Voltage	$V_{IN} \leq -10\text{mV}$ , $I_{OUT} = 25\text{mA}$ $T_A = 25^\circ\text{C}$		0.75	1.5	V
Output Leakage Current	$V_{IN} \geq 10\text{mV}$ , $V_{OUT} = 35\text{V}$ $T_A = 25^\circ\text{C}$		0.2	10	$\mu\text{A}$
Input Offset Voltage (Note 3)	$R_S \leq 5k$			10	mV
Input Offset Current (Note 3)				300	nA
Input Bias Current				1200	nA
Input Voltage Range	$V_S = \pm 15\text{V}$ $V^+ = 5\text{V}$ , $V^- = 0$	1	$\pm 13$	3	V
Saturation Voltage	$V^+ \geq 4.5\text{V}$ , $V^- = 0$ $V_{IN} \leq -10\text{mV}$ , $I_{SINK} \leq 3.2\text{mA}$		0.3	0.4	V
Differential Input Voltage				$\pm 5$	V
Positive Supply Current	$T_A = 25^\circ\text{C}$ , $V^+ = 5\text{V}$ , $V^- = 0$		4.3		mA
Positive Supply Current	$T_A = 25^\circ\text{C}$ , $V_S = \pm 15\text{V}$		8	12.5	mA
Negative Supply Current	$T_A = 25^\circ\text{C}$ , $V_S = \pm 15\text{V}$		3	5	mA

### NOTES

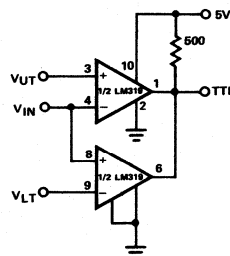
- For supply voltages less than  $\pm 15\text{V}$  the absolute maximum input voltage is equal to the supply voltage.
- These specifications apply for  $V_S = \pm 15\text{V}$  and  $0^\circ\text{C} \leq T_A \leq 70^\circ\text{C}$ , unless otherwise stated. The offset voltage, offset current and bias current specifications apply for any supply voltage from a single 5V supply up to  $\pm 15\text{V}$  supplies.
- The offset voltages and offset currents given are the maximum values required to drive the output within a volt of either supply with a 1mA load. Thus, these parameters define an error band and take into account the worst case effects of voltage gain and input impedance.
- The response time specified is for a 100mV input step with 5mV overdrive.

## TYPICAL APPLICATIONS

### RELAY DRIVER



### WINDOW DETECTOR

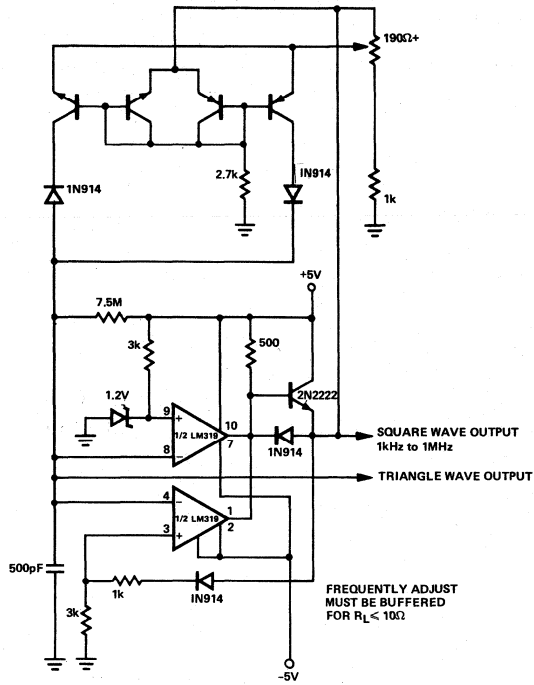


$V_{OUT} = 5\text{V}$  FOR  $V_{LT} < V_{IN} < V_{UT}$   
 $V_{OUT} = 0$  FOR  $V_{IN} < V_{LT}$  OR  $V_{IN} > V_{UT}$



TYPICAL APPLICATIONS (Cont'd)

WIDE RANGE VARIABLE OSCILLATOR



## SIGNETICS DEFINITION OF TERMS

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### OP AMPS

**AVERAGE INPUT OFFSET CURRENT  $t^{\circ}$  COEFF** – The change in input offset current divided by the change in ambient temperature producing it.

**AVERAGE INPUT OFFSET VOLTAGE  $t^{\circ}$  COEFF** – The change in input offset voltage divided by the change in ambient temperature producing it.

**COMMON MODE INPUT RESISTANCE** – The resistance looking into both inputs tied together.

**COMMON MODE REJECTION RATIO (CMRR)** – The ratio of the change of input offset voltage to the input common mode voltage change producing it.

**FULL POWER BANDWIDTH** – The maximum frequency at which the full sinewave output might be obtained.

**INPUT BIAS CURRENT** – The average of the two input currents at zero output voltage. In some cases, the input current for either input independently.

**INPUT CAPACITANCE** – The capacitance looking into either input terminal with the other grounded.

**INPUT CURRENT** – The current into an input terminal.

**INPUT NOISE VOLTAGE** – The square root of the mean square narrow-band noise voltage referred to the input.

**INPUT OFFSET CURRENT** – The difference in the currents into the two input terminals with the output at zero volts.

**INPUT OFFSET VOLTAGE** – That voltage which must be applied between the input terminals to obtain zero output voltage. The input offset voltage may also be defined for the case where two equal resistances are inserted in series with the input leads.

**INPUT RESISTANCE** – The resistance looking into either input terminal with the other grounded.

**INPUT VOLTAGE RANGE** – The range of voltages on the input terminals for which the amplifier operates within specifications. In some cases, the input offset specifications apply over the input voltage range.

**LARGE-SIGNAL VOLTAGE GAIN** – The ratio of the maximum output voltage swing to the change in input voltage required to drive the output to this voltage.

**OUTPUT RESISTANCE** – The resistance seen looking into the output terminal with the output at null. This parameter is defined only under small signal conditions at frequencies above a few hundred cycles to eliminate the influence of drift and thermal feedback.

**OUTPUT SHORT-CIRCUIT CURRENT** – The maximum output current available from the amplifier with the output shorted to ground or to either supply.

**OUTPUT VOLTAGE SWING** – The peak output swing, referred to zero, that can be obtained.

**POWER CONSUMPTION** – The DC power required to operate the amplifier with the output at zero and with no load current.

**POWER SUPPLY REJECTION RATIO** – The ratio of the change in input offset voltage to the change in supply voltages producing it.

**RISE TIME** – The time required for an output voltage step to change from 10% to 90% of its final value.

**SLEW RATE** – The maximum rate of change of output voltage under large signal condition.

**SUPPLY CURRENT** – The current required from the power supply to operate the amplifier with no load and the output at zero.

**TEMPERATURE STABILITY OF VOLTAGE GAIN** – The maximum variation of the voltage gain over the specified temperature range.

### REGULATORS

**DROPOUT VOLTAGE** – The input-output voltage differential at which the circuit ceases to regulate against further reductions in input voltage.

**INPUT-OUTPUT VOLTAGE DIFFERENTIAL** – The range of voltage difference between the supply voltage and the regulated output voltage over which the regulator will operate.

**LINE REGULATOR** – The percentage change in output voltage for a specified change in input voltage.

**LOAD REGULATOR** – The percentage change in output voltage for a specified change in load current.

**MAXIMUM POWER DISSIPATION** – The maximum total device dissipation for which the regulator will operate within specifications.

**OUTPUT NOISE VOLTAGE** – The rms output noise voltage with constant load and no input ripple.

**OUTPUT VOLTAGE RANGE** – The range of output voltage over which the regulator will operate.

**QUIESCENT CURRENT** – That part of input current to the regulator that is not delivered to the load.

### REGULATORS (Cont'd.)

**REFERENCE VOLTAGE** — The output of the reference amplifier measured with respect to the negative supply.

**RIPPLE REJECTION** — The ratio of the peak-to-peak input ripple voltage to the peak-to-peak output ripple voltage.

**SENSE VOLTAGE** — The voltage between current sense and current limit terminals necessary to cause current limiting.

**SHORT CIRCUIT CURRENT LIMIT** — The output current of the regulator with the output shorted to the negative supply.

**STANDBY CURRENT DRAIN** — The supply current drawn by the regulator with no output load and no reference voltage load.

### COMPARATORS/SENSE INTERFACE

**COMMON MODE FIRING VOLTAGE** — The CM input voltage that exceeds the dynamic range of the inputs with strobe enabled resulting in the output switching states.

**COMMON MODE RECOVERY TIME** — The time from the turn off of the CM signal to the analog input threshold of the earliest sense line pulse signal that can be processed normally. Processed normally refers to bi-polar signals greater than or less than the input threshold with a corresponding proper output.

**EQUIVALENT INPUT COMMON MODE NOISE VOLTAGE** — The change in input offset voltage due to common mode input noise.

**LOGIC INPUT HIGH VOLTAGE** — The minimum voltage allowed at a bit control gate to hold the bit off.

**LOGIC INPUT LOW VOLTAGE** — The maximum voltage allowed at a bit control gate to hold the bit on.

**OUTPUT SINK CURRENT** — The maximum negative current that can be delivered by the comparator.

**PEAK OUTPUT CURRENT** — The maximum current that may flow into the output load without causing damage to the comparator.

**PROPAGATION DELAY** — The interval between the application of an input voltage step and its arrival at either output, measured at 50% of the final value.

**RESPONSE TIME** — The interval between the application of an input step function and the time when the output crosses the logic threshold voltage. The input step drives the comparator from some initial, saturated input voltage

to an input level just barely in excess of that required to bring the output from saturation to the logic threshold voltage overdrive.

**STROBE CURRENT** — The maximum current drawn by the strobe terminals when it is at the zero logic level.

**STROBE DELAY** — The time delay measured from strobe to output threshold with a signal present exceeding the input threshold.

**STROBE RELEASE TIME** — The time required for the output to rise to the logic threshold voltage after the strobe terminal has been driven from the zero to the one logic level. Appropriate input conditions are assumed.

**STROBED OUTPUT LEVEL** — The DC output voltage, independent of input voltage, with the voltage on the strobe terminal equal to or less than a minimum specified amount.

**SWITCHING SPEED** — The time required to turn on the least significant bit.

**THRESHOLD UNCERTAINTY** — With all sense amps sharing the same input threshold less the uncertainty as a "0". This includes unit to unit, power supply and temperature variations.

**THRESHOLD VOLTAGE** — The typical referred to input voltage which determines whether an input is a "1" or a "0". A signal whose magnitude is greater than the threshold level is sensed as a logic "1" and a signal whose magnitude is less as a "0".

**ZERO SCALE OUTPUT CURRENT** — The output current for all bits turned off.

### COMMUNICATIONS CIRCUITS

**AGC DETECTOR SENSITIVITY** — The ratio of the incremental differential DC voltage change at the AGC Detector Output Terminals to the incremental change in peak-to-peak voltage at the AGC Detector Input Terminal for a specified burst input level, with the local oscillator locked.

**APC DETECTOR SENSITIVITY** — The ratio of the incremental differential DC voltage change at the APC Detector Output Terminals to the incremental change in relative phase at the APC Detector Input Terminal for a specified burst input level.

**AVERAGE TEMPERATURE COEFFICIENT OF OUTPUT VOLTAGE** — The percentage change in output voltage for a specified change in ambient temperature.

**BANDWIDTH** — The frequency at which the differential gain is 3dB below its low frequency value.

## **SIGNETICS DEFINITION OF TERMS**

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### **COMMUNICATIONS CIRCUITS (Cont'd)**

**DIFFERENTIAL OUTPUT VOLTAGE SWING** — The peak differential output swing that can be obtained without clipping.

**DIFFERENTIAL VOLTAGE GAIN** — The ratio of the change in differential output voltage to the change in differential input voltage producing it.

**OSCILLATOR CONTROL SENSITIVITY** — The ratio of the incremental change in oscillator free running frequency to the incremental change in the differential DC voltage at the APC Detector Output Terminals.

**OUTPUT COMMON MODE VOLTAGE** — The average of the voltages at the two output terminals.

**OUTPUT OFFSET VOLTAGE** — The difference between the voltages at the two output terminals with the inputs grounded.

**TOTAL HARMONIC DISTORTION** — The ratio of the sum of the amplitudes of all signals harmonically related to the fundamental, and the amplitude of the fundamental signal.

**signetics**

MOS  
PRODUCT  
SPECIFICATIONS

7



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## MOS Functional Index

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## SIGNETICS MOS SHIFT REGISTER SELECTION GUIDE

PART NUMBER	CAPACITY	OPERATION	OUTPUT STRUCTURE	ON CHIP RE-CIRCULATE	PACKAGE NO. of LEADS	TYP SPEED	NUMBER OF CLOCKS	CLOCK TTL COMPATABILITY	POWER SUPPLIES
2533	1024 BITS	STATIC	Push Pull	JUMPER	V-8	2.0 MHz	ONE	YES	+5, -12
2509	Dual 50 BITS	STATIC	Tri-state	YES	A-14, K-10	3.0 MHz	ONE	YES	+5, -5, -12
2510	Dual 100 BITS	STATIC	Tri-state	YES	A-14, K-10	3.0 MHz	ONE	YES	+5, -5, -12
2521	Dual 128 BITS	STATIC	Push Pull	YES	V-8	3.0 MHz	ONE	YES	+5, -12
2522	Dual 132 BITS	STATIC	Push Pull	YES	V-8	3.0 MHz	ONE	YES	+5, -12
2511	Dual 200 BITS	STATIC	Tri-state	YES	A-14, K-10	3.0 MHz	ONE	YES	+5, -5, -12
2527	Dual 256 BITS	STATIC	Push Pull	YES	V-8	3.0 MHz	ONE	YES	+5, -12
2532	Quad 80 BITS	STATIC	Push Pull	YES	B-16	3.0 MHz	ONE	YES	+5, -12
2518	Hex 32 BITS	STATIC	Bare Drain	YES	B-16	3.0 MHz	ONE	YES	+5, -12
2519	Hex 40 BITS	STATIC	Bare Drain	YES	B-16	3.0 MHz	ONE	YES	+5, -12
2505	512 BITS	DYNAMIC	Bare Drain	YES	K-10	3.0 MHz	TWO	NO	+5, -5
2524	512 BITS	DYNAMIC	Bare Drain	YES	V-8	5.0 MHz	TWO	NO	+5, -5
2504	1024 BITS	DYNAMIC	Bare Drain	NO	TA-8, V-8	10.0 MHz	TWO	NO	+5, -5
2512	1024 BITS	DYNAMIC	Bare Drain	YES	K-10	3.0 MHz	TWO	NO	+5, -5
2525	1024 BITS	DYNAMIC	Bare Drain	YES	V-8	5.0 MHz	TWO	NO	+5, -5
2506	Dual 100 BITS	DYNAMIC	Bare Drain	NO	T-8, V-8	4.0 MHz	TWO	NO	+5, -5
2507	Dual 100 BITS	DYNAMIC	7.5K PD	NO	T-8, V-8	4.0 MHz	TWO	NO	+5, -5
2517	Dual 100 BITS	DYNAMIC	20K PD	NO	T-8, V-8	4.0 MHz	TWO	NO	+5, -5
2503	Dual 512 BITS	DYNAMIC	Bare Drain	NO	TA-8, V-8	10.0 MHz	TWO	NO	+5, -5
2502	Quad 256 BITS	DYNAMIC	Bare Drain	NO	B-16	10.0 MHz	TWO	NO	+5, -5



### SILICON GATE 2500 SERIES

#### DESCRIPTION

The Signetics 1103 is designed for main memory applications where high performance, low cost and large bit storage are important design objectives. It is a 1024 word by 1 bit random access memory element using enhancement mode P-channel MOS devices integrated on a monolithic array. It is fully decoded, permitting the use of an 18-pin dual in-line package. The dynamic circuitry dissipates significant power only during precharge. Information stored in the memory is nondestructively read. Refreshing of all 1024 bits is accomplished in 32 read cycles and is required every two milliseconds. A separate cenable (chip enable) lead allows easy selection of an individual package when outputs are OR-tied. Use Signetics 8T25 Sense Amp, and 3207 Clock Driver.

#### FEATURES

- **LOW POWER DISSIPATION** — DISSIPATES POWER PRIMARILY ON SELECTED CHIPS
- **ACCESS TIME** — 300 nsec.
- **CYCLE TIME** — 580 nsec.
- **REFRESH PERIOD** — 2 MILLISECONDS FOR 0-70°C AMBIENT
- **OR-TIE CAPABILITY**
- **SIMPLE MEMORY EXPANSION WITH CHIP ENABLE**
- **FULLY DECODED** — ON-CHIP ADDRESS DECODE
- **INPUTS PROTECTED** — ALL INPUTS HAVE PROTECTION AGAINST STATIC CHARGE.
- **LOW COST PACKAGING** — 18 PIN SILICONE AND 18 PIN CERAMIC DUAL IN-LINE

#### APPLICATIONS

CORE MEMORY REPLACEMENT  
BUFFER STORES  
MAIN MEMORY

#### PROCESS TECHNOLOGY

The use of Signetics' unique silicon gate low threshold process allows the design and production of higher performance MOS circuits and provides higher functional density on a chip than other MOS technologies.

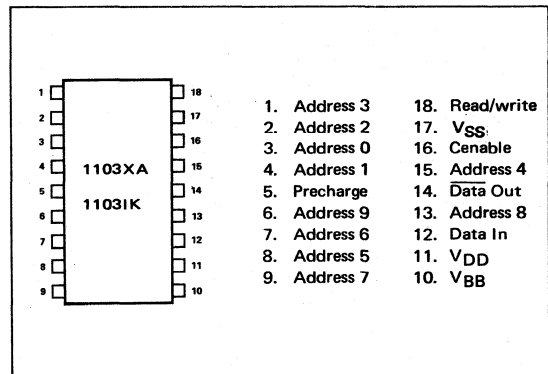
#### SILICON PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process, the silicon material over the gate oxide passivates the MOS transistors, and the deposited dielectric

#### SILICONE PACKAGING (Cont'd)

material over the silicon gate-oxide-substrate structure provides an ion barrier. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability and demonstrating superior moisture resistance, mechanical shock and ionic contamination barriers.

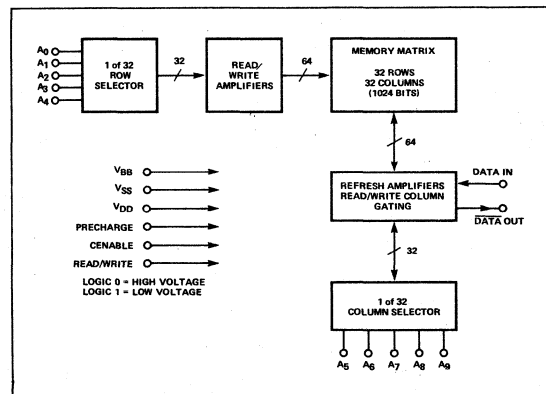
#### PIN CONFIGURATION (Top View)



#### PART IDENTIFICATION TABLE

TYPE	PACKAGE	OP. TEMP. RANGE
1103XA	18-Pin DIP Silicone	0-70°C
11031K	18-Pin DIP Ceramic	0-70°C

#### BLOCK DIAGRAM



**MAXIMUM GUARANTEED RATINGS<sup>(10)</sup>**

Operating Ambient Temperature	0°C to 70°C	Supply Voltages $V_{DD}$ and $V_{SS}$	
Storage Temperature	-65°C to +150°C	with Respect to $V_{BB}$	-25V to +0.8V
All Input or Output Voltages		Power Dissipation	1.0W
with Respect to the Most			
Positive Supply Voltage, $V_{BB}$	-25V to +0.8V		

**D.C. AND OPERATING CHARACTERISTICS**

$T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{SS}^{(1)} = 16\text{V} \pm 5\%$ ,  $(V_{BB} - V_{SS})^{(6)} = 3\text{V}$  to  $4\text{V}$ ,  $V_{DD} = 0\text{V}$  unless otherwise specified (Note 9),

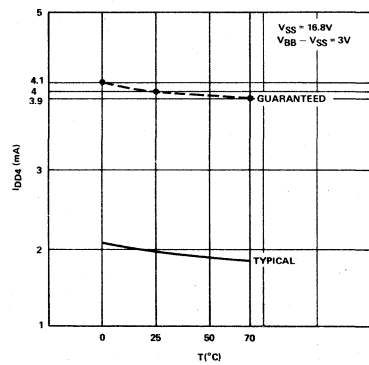
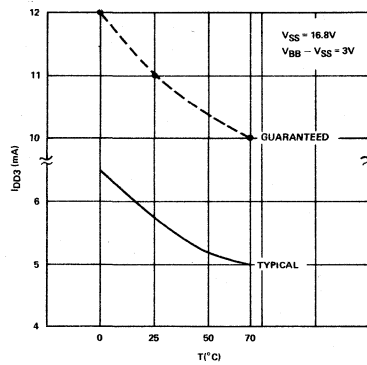
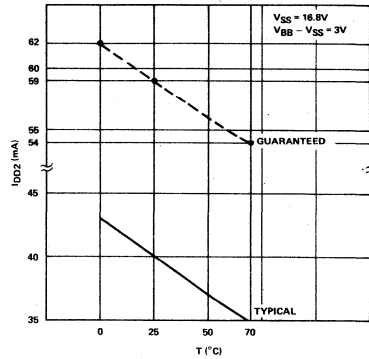
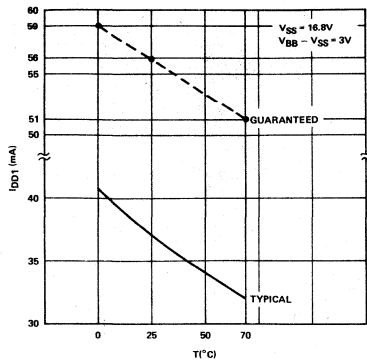
SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$I_{LI}$	Input Load Current (All input pins)			1	$\mu\text{A}$	$V_{IN} = 0\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{LO}$	Output Leakage Current			1	$\mu\text{A}$	$V_{OUT} = 0\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{BB}$	$V_{BB}$ Supply Current			100	$\mu\text{A}$	
$I_{DD1}^{(2)}$	Supply Current During $t_{PC}$		37	56	mA	All Addresses = 0V Precharge = 0V Cenable = $V_{SS}$ ; $T_A = 25^\circ\text{C}$
$I_{DD2}^{(2)}$	Supply Current During $t_{OV}$		38	59	mA	All Addresses = 0V Precharge = 0V Cenable = 0V; $T_A = 25^\circ\text{C}$
$I_{DD3}^{(2)}$	Supply Current During $t_{POV}$		5.5	11	mA	Precharge = $V_{SS}$ Cenable = 0V; $T_A = 25^\circ\text{C}$
$I_{DD4}^{(2)}$	Supply Current During $t_{CP}$		3	4	mA	Precharge = $V_{SS}$ Cenable = $V_{SS}$ ; $T_A = 25^\circ\text{C}$
$I_{DD}^{(5)AV}$	Average Supply Current		17	25	mA	Cycle Time = 580 ns; Precharge Width = 190 ns; $T_A = 25^\circ\text{C}$
$V_{IL1}^{(7)}$	Input Low Voltage (All Address & Data-in Lines)	$V_{SS}-17$		$V_{SS}-14.2$	V	$T_A = 0^\circ\text{C}$
$V_{IL2}^{(7)}$	Input Low Voltage (All Address & Data-in Lines)	$V_{SS}-17$		$V_{SS}-14.5$	V	$T_A = 70^\circ\text{C}$
$V_{IL3}^{(7,8)}$	Input Low Voltage (Precharge Cenable & Read/Write Inputs)	$V_{SS}-17$		$V_{SS}-14.7$	V	$T_A = 0^\circ\text{C}$
$V_{IL4}^{(7,8)}$	Input Low Voltage (Precharge Cenable & Read/Write Inputs)	$V_{SS}-17$		$V_{SS}-15.0$	V	$T_A = 70^\circ\text{C}$
$V_{IH1}^{(7)}$	Input High Voltage (All Inputs)	$V_{SS}-1$		$V_{SS}+1$	V	$T_A = 0^\circ\text{C}$
$V_{IH2}^{(7)}$	Input High Voltage (All Inputs)	$V_{SS}-0.7$		$V_{SS}+1$	V	$T_A = 70^\circ\text{C}$
$I_{OH1}$	Output High Current	600	900	4000	$\mu\text{A}$	} $R_{LOAD} = 100\Omega^{(4)}$
$I_{OH2}$	Output High Current	500	800	4000	$\mu\text{A}$	
$I_{OL}$	Output Low Current	See Note 3				
$V_{OH1}$	Output High Voltage	60	90	400	mV	
$V_{OH2}$	Output High Voltage	50	80	400	mV	
$V_{OL}$	Output Low Voltage	See Note 3				

**NOTES**

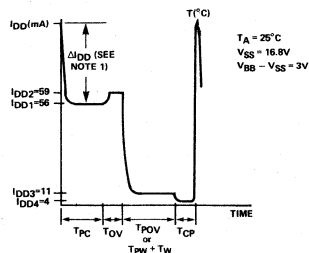
- The  $V_{SS}$  current drain is equal to  $(I_{DD} + I_{OH})$  or  $(I_{DD} + I_{OL})$ .
- See Supply Current vs. Temperature (p. 3) for guaranteed current at the temperature extremes. These values are taken from a single pulse measurement.
- The output current when reading a low output is the leakage current of the 1103 plus external noise coupled into the output line from the clocks.  $V_{OL}$  equals  $I_{OL}$  across the load resistor.
- This value of load resistance is used for measurement purposes. In applications the resistance may range from  $100\Omega$  to  $1\text{ k}\Omega$ .
- This parameter is periodically sampled and is not 100% tested.
- $(V_{BB} - V_{SS})$  supply should be applied at or before  $V_{SS}$ .
- The maximum values for  $V_{IL}$  and the minimum values for  $V_{IH}$  are linearly related to temperature between  $0^\circ\text{C}$  and  $70^\circ\text{C}$ . Thus any value between  $0^\circ\text{C}$  and  $70^\circ\text{C}$  can be calculated using a straight-line relationship.
- The maximum values for  $V_{IL}$  (for precharge, cenable & read/write) may be increased to  $V_{SS}-14.2$  @  $0^\circ\text{C}$  and  $V_{SS}-14.5$  @  $70^\circ\text{C}$  (same values as those specified for the address and data-in lines) with a 40 ns degradation (worst case) in  $t_{AC}$ ,  $t_{PC}$ ,  $t_{RC}$ ,  $t_{WC}$ ,  $t_{RWC}$ ,  $t_{ACC1}$  and  $t_{ACC2}$ .
- Manufacturer reserves the right to make design and process changes and improvements.
- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

CHARACTERISTIC CURVES

SUPPLY CURRENT VS TEMPERATURE



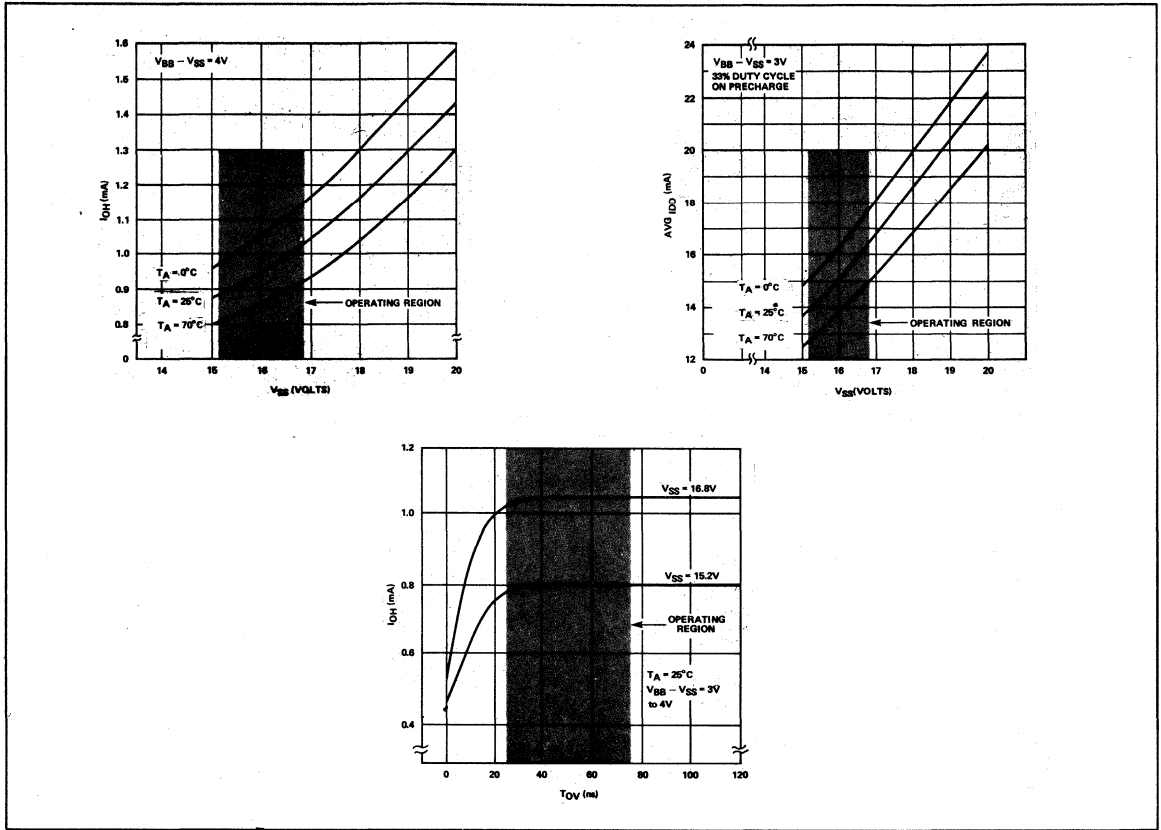
I<sub>DD</sub> VS TIME



NOTES:

1.  $\Delta I_{DD}$  is due to charging of internal device node capacitance at precharge.
2. These values are taken from a single pulse measurement.

CHARACTERISTIC CURVES (Cont'd)



AC CHARACTERISTICS  $T_A = 0^\circ C$  to  $+70^\circ C$ ,  $V_{SS} = 16 \pm 5\%$ ,  $(V_{BB} - V_{SS}) = 3.0V$  to  $4.0V$ ,  $V_{DD} = 0$   
 READ, WRITE, AND READ/WRITE CYCLE

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$t_{REF}$	Time Between Refresh			2	ms	
$t_{AC(1)}$	Address to Cenable Set Up Time	115			ns	
$t_{CA}$	Cenable to Address Hold Time	20			ns	
$t_{PC(1)}$	Precharge to Cenable Delay	125			ns	
$t_{OVL}$	Precharge & Cenable Overlap, Low	25		75	ns	
$t_{CP}$	Cenable to Precharge Delay	85			ns	
$t_{OVH}$	Precharge & Cenable Overlap, High			140	ns	

READ CYCLE

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$t_{RC(1)}$	Read Cycle	480			ns	$t_r = 20$ ns $C_{LOAD} = 100$ pF $R_{LOAD} = 100\Omega$ $V_{REF} = 40$ mV
$t_{POV}$	Precharge to End of Cenable	165		500	ns	
$t_{PO}$	End of Precharge to Output Delay			120	ns	
$t_{ACC1(1)}$	Address to Output Access	300			ns	
$t_{ACC2(1)}$	Precharge to Output Access	310			ns	

AC CHARACTERISTICS(Cont'd)

WRITE OR READ/WRITE CYCLE

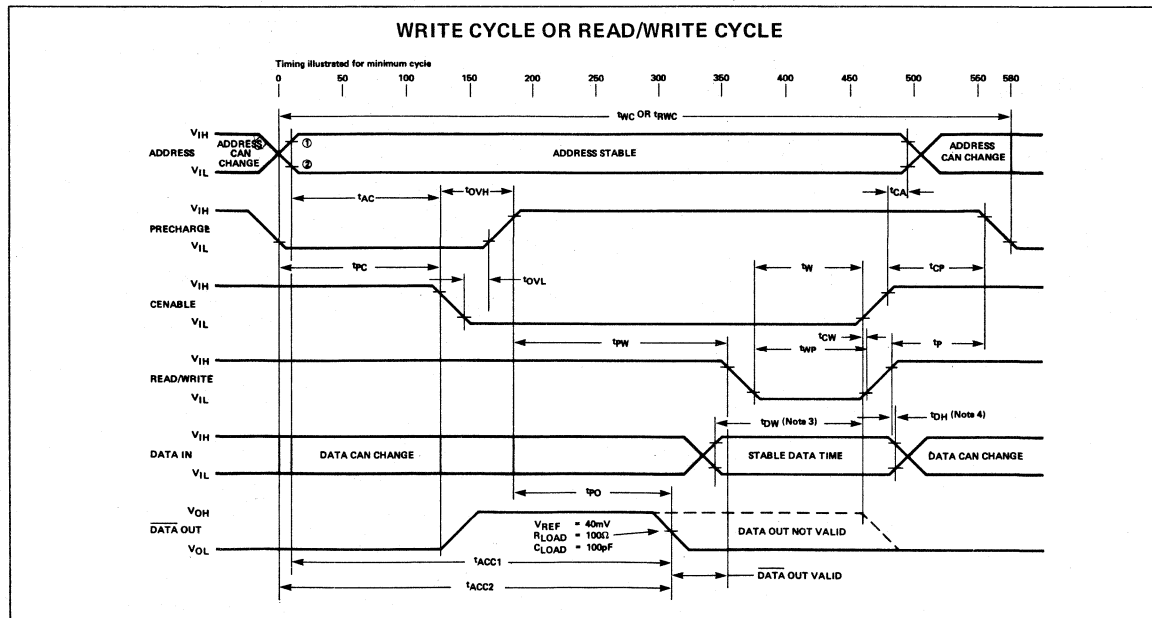
SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$t_{WC(1)}$	Write Cycle	580			ns	$t_{\tau} = 20 \text{ ns}$  $C_{LOAD} = 100 \text{ pF}$ $R_{LOAD} = 100\Omega$ $V_{REF} = 40 \text{ mV}$
$t_{RWC(1)}$	Read/Write Cycle	580			ns	
$t_{PW}$	Precharge to Read/Write Delay	165		500	ns	
$t_{WP}$	Read/Write Pulse Width	50			ns	
$t_W$	Read/Write Set Up Time	80			ns	
$t_{DW}$	Data Set Up Time	105			ns	
$t_{DH}$	Data Hold Time	10			ns	
$t_{PO}$	End of Precharge to Output Delay			120	ns	
$t_p$	Time to Next Precharge	0			ns	
$t_{CW}$	Read/Write Hold Time			10	ns	

CAPACITANCE (note 2)

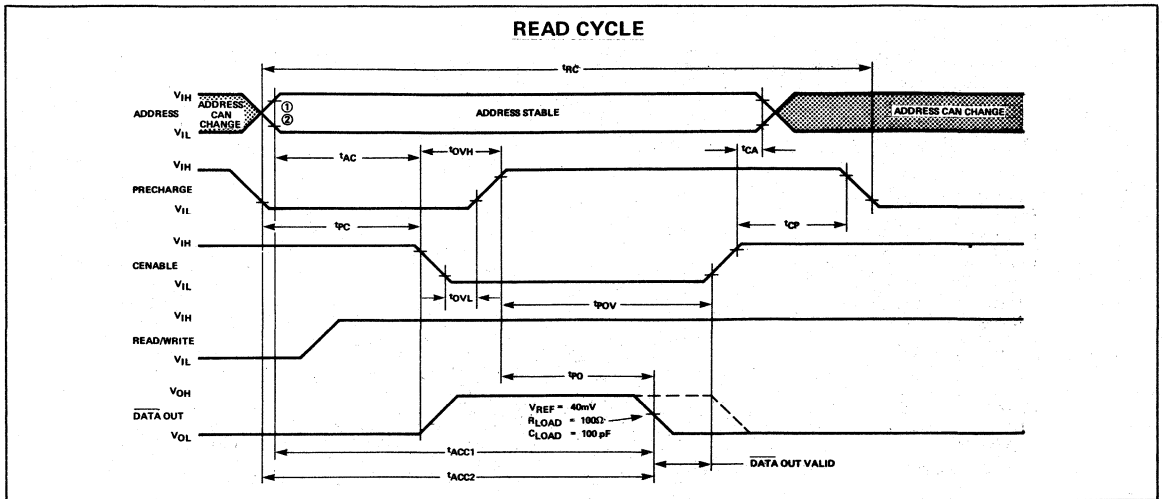
SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$C_{AD}$	Address Capacitance		5	7	pF	$V_{IN} = V_{SS}$ $V_{IN} = V_{SS}$ $V_{IN} = V_{SS}$ $V_{IN} = V_{SS}$ $V_{IN} = V_{SS}$ $V_{IN} = V_{SS}$ $V_{OUT} = 0V$  $f = 1 \text{ MHz}$ All Unused Pins are at A.C. Ground
$C_{PR}$	Precharge Capacitance		15	18	pF	
$C_{CE}$	Cenable Capacitance		15	18	pF	
$C_{RW}$	Read/Write Capacitance		11	15	pF	
$C_{IN1}$	Data Input Capacitance		4	5	pF	
$C_{IN2}$	Data Input Capacitance		2	4	pF	
$C_{OUT}$	Data Output Capacitance		2	3	pF	

- (1) These times will degrade by 40 ns (worst case) if the maximum values for  $V_{IL}$  (for precharge, cenable and read/write inputs) go to  $V_{SS} - 14.2V$  @  $0^{\circ}C$  and  $V_{SS} - 14.5V$  @  $70^{\circ}C$  as defined on page 2.
- (2) This parameter is periodically sampled and is not 100% tested. It is measured at worst case operating conditions. Capacitance measurements for plastic packages only.

TIMING DIAGRAM



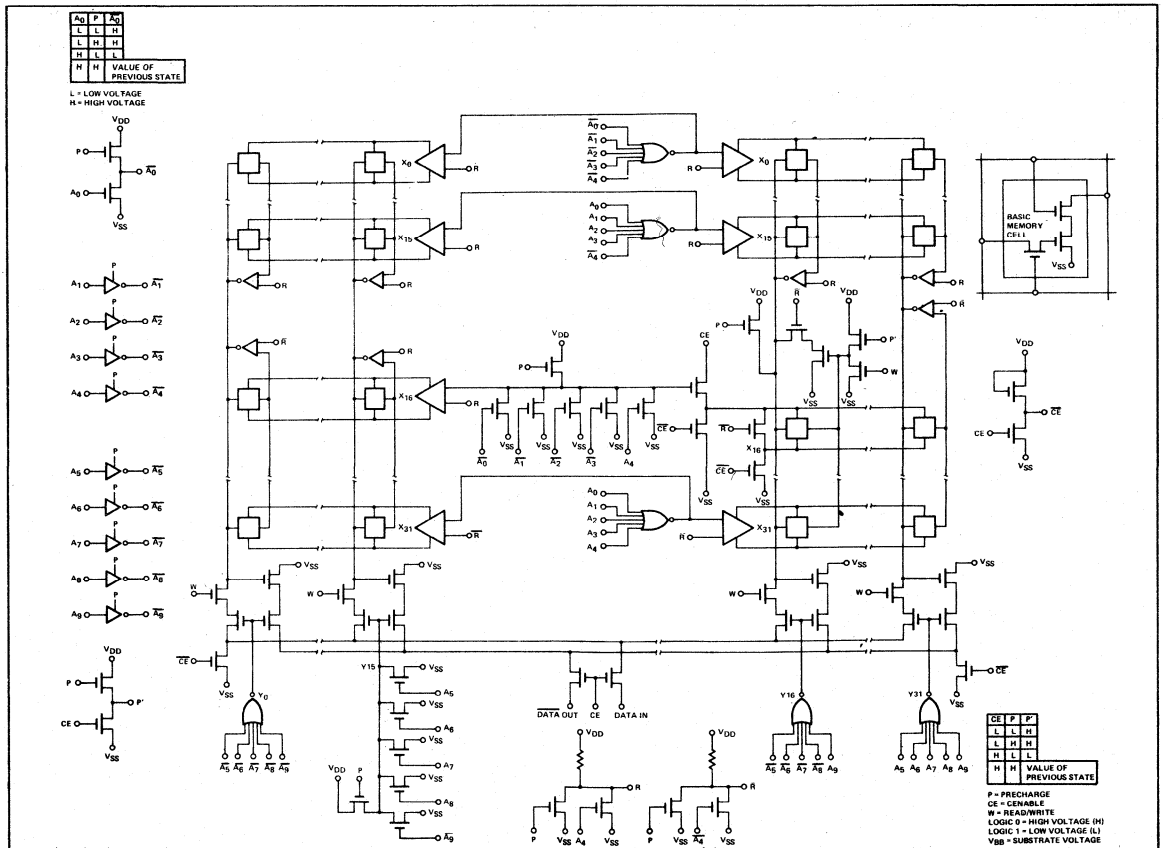
TIMING DIAGRAM (Cont'd)



NOTES:

- ①  $V_{DD} + 2V$
- ②  $V_{SS} - 2V$
- 3  $t_{DW}$  is referenced to point ② of the rising edge of cenable or read/write whichever occurs first.
- 4  $t_{DH}$  is referenced to point ① of the rising edge of cenable or read/write whichever occurs first.

CIRCUIT SCHEMATIC





### SILICON GATE MOS

#### DESCRIPTION

The Signetics 1103-1 is designed for main memory applications where high performance, low cost and large bit storage are important design objectives. It is a 1024 word by 1 bit random access memory element using enhancement mode P-channel MOS devices integrated on a monolithic array. It is fully decoded, permitting the use of an 18-pin dual in-line package. The dynamic circuitry dissipates significant power only during precharge. Information stored in the memory is nondestructively read. Refreshing of all 1024 bits is accomplished in 32 read cycles and is required every two milliseconds. A separate cenable (chip enable) lead allows easy selection of an individual package when outputs are OR-tied. Use Signetics 8T28 Sense Amp, and 3207 Clock Driver.

#### FEATURES

- **LOW POWER DISSIPATION – DISSIPATES POWER PRIMARILY ON SELECTED CHIPS**
- **ACCESS TIME – 150 nsec.**
- **CYCLE TIME – 340 nsec.**
- **REFRESH PERIOD – 1 MILLISECOND FOR 0-55°C AMBIENT**
- **OR-TIE CAPABILITY**
- **SIMPLE MEMORY EXPANSION WITH CHIP ENABLE**
- **FULLY DECODED – ON-CHIP ADDRESS DECODE**
- **INPUTS PROTECTED – ALL INPUTS HAVE PROTECTION AGAINST STATIC CHARGE**
- **LOW COST PACKAGING – 18 PIN SILICONE AND 18 PIN CERAMIC DUAL IN-LINE**

#### APPLICATIONS

CORE MEMORY REPLACEMENT  
BUFFER STORES  
MAIN MEMORY

#### PROCESS TECHNOLOGY

The use of Signetics' unique silicon gate low threshold process allows the design and production of higher performance MOS circuits and provides higher functional density on a chip than other MOS technologies.

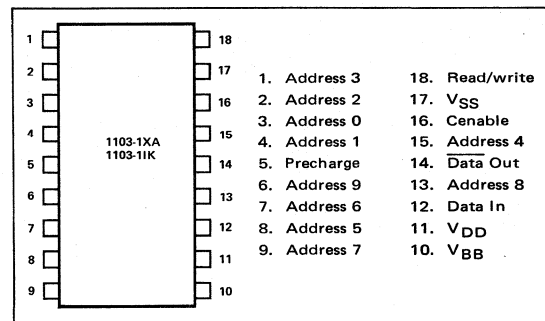
#### SILICON PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process, the silicon material over the gate oxide passivates the MOS transistors, and the deposited dielectric

#### SILICONE PACKAGING (Cont'd)

material over the silicon gate-oxide substrate structure provides an ion barrier. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability and demonstrating superior moisture resistance, mechanical shock and ionic contamination barriers.

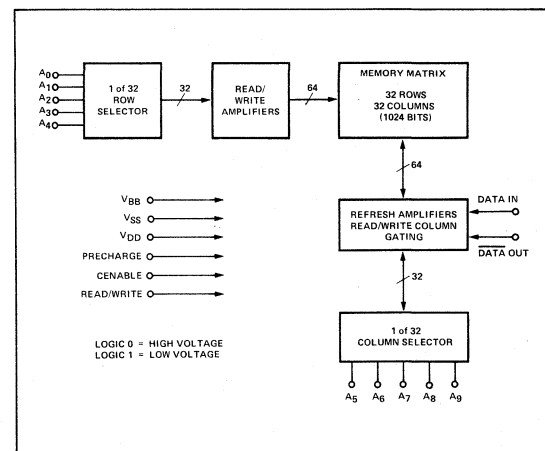
#### PIN CONFIGURATION (Top View)



#### PART IDENTIFICATION TABLE

TYPE	PACKAGE	OP. TEMP RANGE
1103-1XA	18-Pin DIP Silicone	0-55°C
1103-11K	18-Pin DIP Ceramic	0-55°C

#### BLOCK DIAGRAM



**AC CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $+55^\circ\text{C}$ ;  $V_{SS} = 19 \pm 5\%$ ,  $(V_{BB} - V_{SS}) = 3.0\text{V}$  to  $4.0\text{V}$ ,  $V_{DD} = 0\text{V}$   
**READ, WRITE, AND READ/WRITE CYCLE**

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$t_{REF}$	Time Between Refresh			1	ms	
$t_{AC}$	Address to Cenable Set Up Time	30			ns	
$t_{CA}$	Cenable to Address Hold Time	10			ns	
$t_{PC}$	Precharge to Cenable Delay	60			ns	
$t_{OVL}$	Precharge & Cenable Overlap, Low	5		30	ns	
$t_{CP}$	Cenable to Precharge Delay	40			ns	
$t_{OVH}$	Precharge & Cenable Overlap, High			85	ns	

**READ CYCLE**

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$t_{RC}^{(1)}$	Read Cycle	300			ns	$t_r = 20\text{ ns}$ $C_{LOAD} = 50\text{ pF}$ $R_{LOAD} = 100\Omega$ $V_{REF} = 80\text{ mV}$
$t_{POV}$	Precharge to End of Cenable	115		500	ns	
$t_{PO}^{(1)}$	End of Precharge to Output Delay			75	ns	
$t_{ACC1}^{(1)}$	Address to Output Access	150			ns	
$t_{ACC2}^{(1)}$	Precharge to Output Access	180			ns	

**WRITE OR READ/WRITE CYCLE**

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$t_{WC}$	Write Cycle	340			ns	$t_r = 20\text{ ns}$
$t_{RWC}^{(1)}$	Read/Write Cycle	340			ns	
$t_{PW}$	Precharge to Read/Write Delay	115		500	ns	$C_{LOAD} = 50\text{ pF}$ $R_{LOAD} = 100\Omega$ $V_{REF} = 80\text{ mV}$
$t_{WP}$	Read/Write Pulse Width	20			ns	
$t_W$	Read/Write Set Up Time	20			ns	
$t_{DW}$	Data Set Up Time	40			ns	
$t_{DH}$	Data Hold Time	10			ns	
$t_{PO}^{(1)}$	End of Precharge to Output Delay			75	ns	
$t_p$	Time to Next Precharge	0			ns	
$t_{CW}$	Read/Write Hold Time			15	ns	

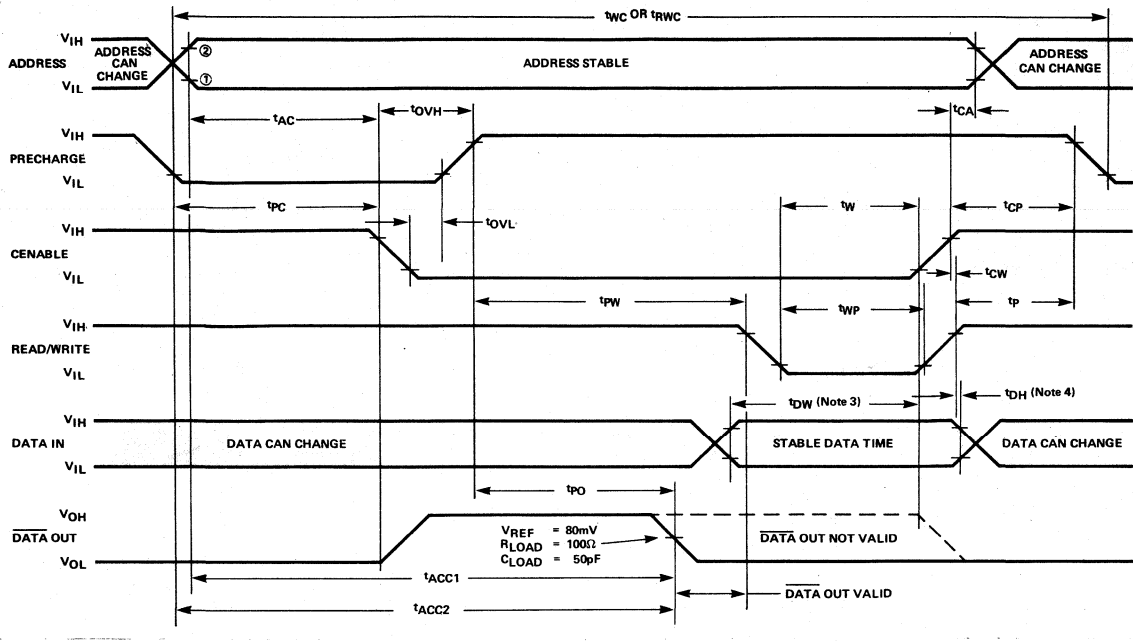
**CAPACITANCE (note 2)**

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$C_{AD}$	Address Capacitance		5	7	pF	$f = 1\text{ MHz}$ All Unused Pins are at A.C. Ground
$C_{PR}$	Precharge Capacitance		15	18	pF	
$C_{CE}$	Cenable Capacitance		15	18	pF	
$C_{RW}$	Read/Write Capacitance		11	15	pF	
$C_{IN1}$	Data Input Capacitance		4	5	pF	
$C_{IN2}$	Data Input Capacitance		2	4	pF	
$C_{OUT}$	Data Output Capacitance		2	3	pF	
					pF	
					pF	
					pF	

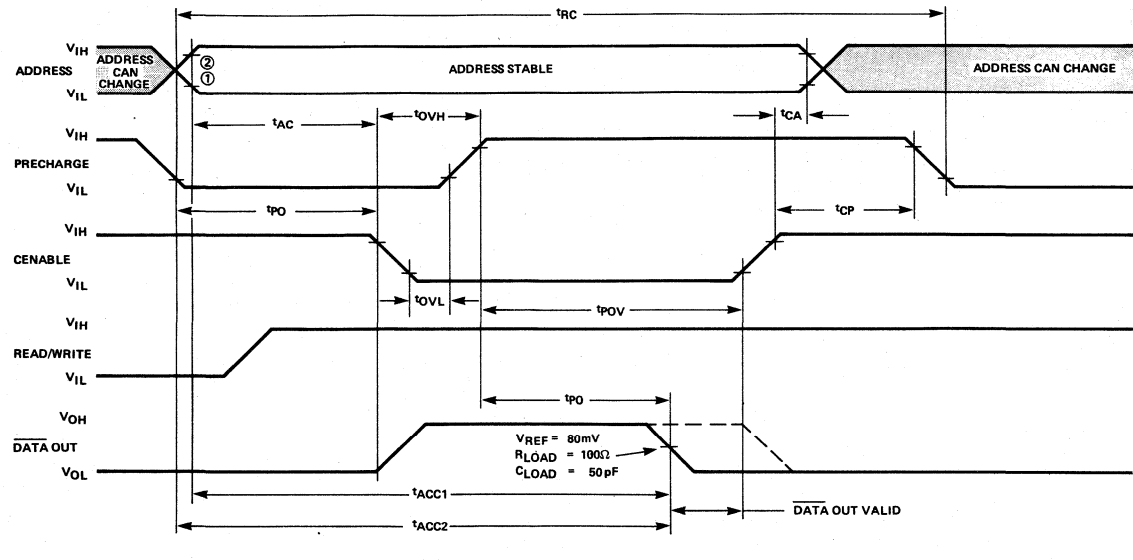
(1) These times will degrade by 35 ns if a  $V_{REF}$  point of 40 mV is chosen instead of the 80 mV point defined in this specification.  
 (2) This parameter is periodically sampled and is not 100% tested. It is measured at worst case operating conditions. Capacitance measurements for plastic packages only.

TIMING DIAGRAM

WRITE CYCLE OR READ/WRITE CYCLE



READ CYCLE



NOTES:

- ①  $V_{DD} + 2V$
  - ②  $V_{SS} - 2V$
- $t_r$  is defined as the transitions between these two points.
- 3  $t_{DW}$  is referenced to point ① of the rising edge of enable or read/write whichever occurs first.
  - 4  $t_{DH}$  is referenced to point ② of the rising edge of enable or read/write whichever occurs first.

**MAXIMUM GUARANTEED RATINGS (8)**

Operating Ambient Temperature	0°C to 55°C	Supply Voltages $V_{DD}$ and $V_{SS}$	
Storage Temperature	-65°C to +150°C	with Respect to $V_{BB}$	-25V to +0.8V
All Input or Output Voltages		Power Dissipation	1.0W
with Respect to the Most Positive Supply Voltage, $V_{BB}$	-25V to +0.8V		

**D.C. AND OPERATING CHARACTERISTICS**
 $T_A = 0^\circ\text{C to } +55^\circ\text{C}$ ,  $V_{SS}^{(1)} = 19\text{V} \pm 5\%$ ,  $(V_{BB} - V_{SS})^{(6)} = 3\text{V to } 4\text{V}$ ,  $V_{DD} = 0\text{V}$  unless otherwise specified (Note 7).

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
$I_{LI}$	Input Load Current (All input pins)			10	$\mu\text{A}$	$V_{IN} = 0\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{LO}$	Output Leakage Current			10	$\mu\text{A}$	$V_{OUT} = 0\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{BB}$	$V_{BB}$ Supply Current			100	$\mu\text{A}$	
$I_{DD1}^{(2)}$	Supply Current During $t_{PC}$		45	60	mA	All Addresses = 0V Precharge = 0V Cenable = $V_{SS}$ ; $T_A = 25^\circ\text{C}$
$I_{DD2}^{(2)}$	Supply Current During $t_{QV}$		50	68.5	mA	All addresses = 0V Precharge = 0V Cenable = 0V; $T_A = 25^\circ\text{C}$
$I_{DD3}^{(2)}$	Supply Current During $t_{POV}$		8.5	11	mA	Precharge = $V_{SS}$ Cenable = 0V; $T_A = 25^\circ\text{C}$
$I_{DD4}^{(2)}$	Supply Current During $t_{CP}$		3	4	mA	Precharge = $V_{SS}$ Cenable = $V_{SS}$ ; $T_A = 25^\circ\text{C}$
$I_{DD}^{(5)AV}$	Average Supply Current		20	23	mA	Precharge Width = 105ns @ 50% Cycle Time = 340 ns; $T_A = 25^\circ\text{C}$
$V_{IL1}$	Input Low Voltage (All address and data-in lines)	$V_{SS}-20$		$V_{SS}-17$	V	
$V_{IH1}$	Input High Voltage (All Inputs)	$V_{SS}-1$		$V_{SS}+1$	V	
$I_{OH1}$	Output High Current	1.15	1.3	7.0	mA	$T_A = 25^\circ\text{C}$ $T_A = 55^\circ\text{C}$ $R_{LOAD} = 100\Omega^{(4)}$
$I_{OH2}$	Output High Current	0.9	1.15	7.0	mA	
$I_{OL}$	Output Low Current	See Note 3				
$V_{OH1}$	Output High Voltage	115	130	700	mV	
$V_{OH2}$	Output High Voltage	90	115	700	mV	
$V_{OL}$	Output Low Voltage	See Note 3				

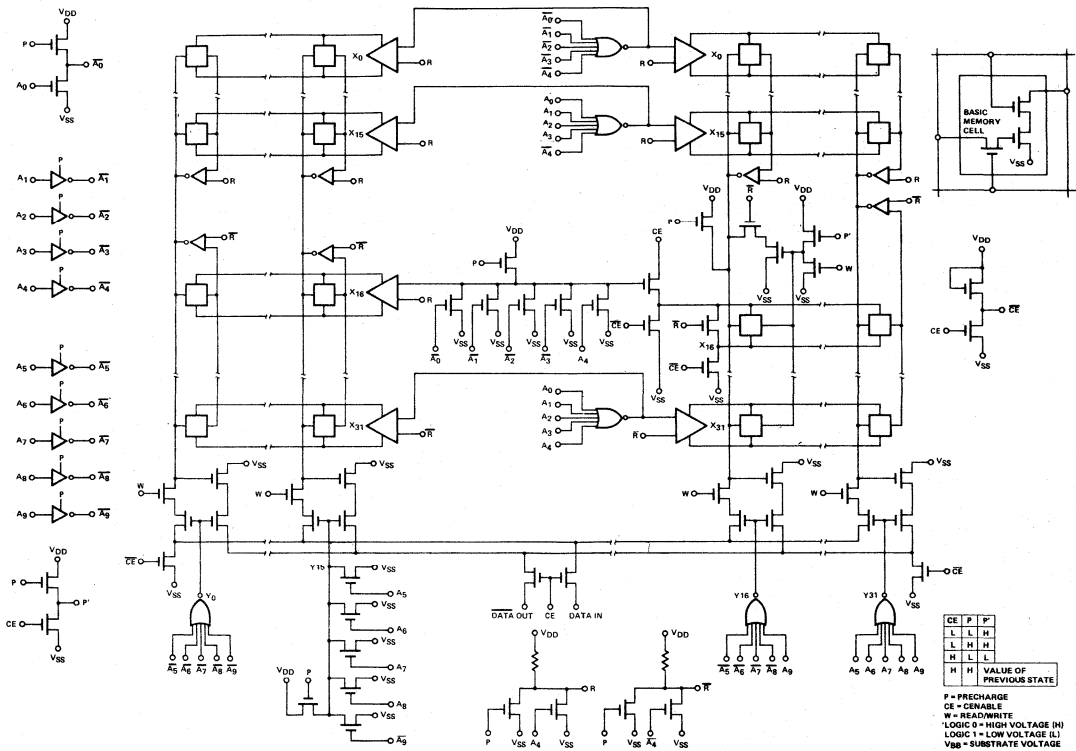
**NOTES:**

- The  $V_{SS}$  current drain is equal to  $(I_{DD} + I_{OH})$  or  $(I_{DD} + I_{OL})$ .
- See Supply Current vs. Temperature (p. 3) for guaranteed current at the temperature extremes. These values are taken from a single pulse measurement.
- The output current when reading a low output is the leakage current of the 1103-1 plus external noise coupled into the output line from the clocks.  $V_{OL}$  equals  $I_{OL}$  across the load resistor.
- This value of load resistance is used for measurement purposes. In applications the resistance may range from 100 $\Omega$  to 1 k $\Omega$ .
- This parameter is periodically sampled and is not 100% tested.
- $(V_{BB} - V_{SS})$  supply should be applied at or before  $V_{SS}$ .
- Manufacturer reserves the right to make design and process changes and improvements.
- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

CIRCUIT SCHEMATIC

A <sub>0</sub>	P	A <sub>0</sub>
L	L	H
L	H	H
H	L	L
H	H	VALUE OF PREVIOUS STATE

L = LOW VOLTAGE  
H = HIGH VOLTAGE



### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

The Signetics 2500 Series 256 x 1 Random Access Memory employs enhancement mode P-channel MOS devices integrated on a single monolithic chip. It is fully decoded, permitting the use of a 16-pin dual in-line package. Complete static operation requires no clocking.

#### FEATURES

- FULLY DECODED ADDRESSES
- ACCESS TIME – 1.0 $\mu$ s GUARANTEED
- POWER DISSIPATION: 1.6mW/BIT MAXIMUM
- STANDBY POWER DISSIPATION: 150 $\mu$ W/BIT
- DTL AND TTL COMPATIBLE
- CHIP SELECT AND OUTPUT WIRED-OR CAPABILITY
- STANDARD 16-PIN DIP
- P-MOS SILICON GATE TECHNOLOGY
- $V_{CC} = +5V, V_{DD} = V_D = -9V$

#### APPLICATIONS

SMALL BUFFER STORES  
SMALL CORE MEMORY REPLACEMENT  
BIPOLAR COMPATIBLE DATA STORAGE

#### SILICONE PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process the silicon material over the gate oxide passivates the MOS transistors, and the deposited dielectric material over the silicon gate-oxide-substrate structure provides an ion barrier. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in a MOS circuit with inherent high reliability and demonstrating superior moisture resistance, mechanical shock and ionic contamination barriers.

#### PROCESS TECHNOLOGY

The use of Signetics' unique Silicon Gate Low Threshold Process allows the design and production of higher performance MOS circuits and provides higher functional density on a chip than other MOS technologies.

#### BIPOLAR COMPATIBILITY

All inputs of the 2501 can be driven directly by standard bipolar integrated circuits (TTL, DTL, etc.). The data output buffers are capable of sinking a minimum of 1.6 mA, sufficient to drive one standard TTL load.

#### POWER DISSIPATION

The maximum power dissipation of 1.6mW/bit is required only during Read or Write. For standby operation, 150 $\mu$ W/bit is obtained by removing  $V_D$  and reducing  $V_{DD}$  to  $-4.0V$ . Removal of  $V_D$  alone will cut power dissipation by a factor of 1.5.

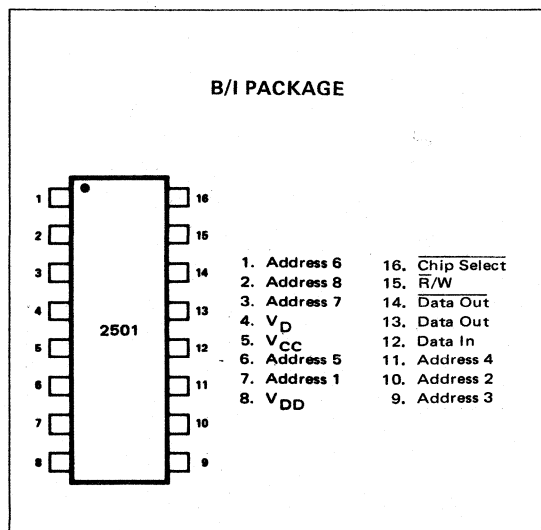
#### SPECIAL FEATURE

The outputs of the 2501 are effectively open circuited when the device is not selected (logic 1 on chip select). This feature allows OR-Tying for memory expansion.

#### PART IDENTIFICATION TABLE

TYPE	PACKAGE	OP. TEMP. RANGE
2501B	16-pin Silicone DIP	0°C. to +70°C.
2501I	16-pin Ceramic DIP	0°C. to +70 C.

#### PIN CONFIGURATION (Top View)



**MAXIMUM GUARANTEED RATINGS (1)**

Operating Temperature	0°C to +70°C
Storage Temperature	-65°C to +150°C
All Input or Output Voltages with Respect to the Most Positive Supply Voltage, V <sub>CC</sub>	+0.3V to -20V
Supply Voltages V <sub>DD</sub> and V <sub>D</sub> with Respect to V <sub>CC</sub>	-18V
Power Dissipation at T <sub>A</sub> = 70°C	640mW

**NOTES:**

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating

- only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and nominal supply voltages.
- V<sub>CC</sub> tolerance is ±5%. Any variation in actual V<sub>CC</sub> will be tracked directly by V<sub>IL</sub>, V<sub>IH</sub> and V<sub>OH</sub> which are stated for a V<sub>CC</sub> of exactly 5 volts.

NOTE: Special devices are available for operation at V<sub>DD</sub> = -7V, V<sub>D</sub> = -10V. Contact your Signetics Representative for details.

**DC CHARACTERISTICS**

(T<sub>A</sub> = 0°C to 70°C, V<sub>CC</sub> = +5V (8), V<sub>DD</sub> = V<sub>D</sub> = -9V ±5%, unless otherwise specified. See notes below)

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current (All Input Pins)		<1.0	500	nA	V <sub>IN</sub> = 0.0V; T <sub>A</sub> = +25°C
I <sub>LO</sub>	Output Leakage Current		<1.0	1000	nA	V <sub>OUT</sub> = 0.0V, Chip Select Input = +3.3V, T <sub>A</sub> = +25°C
I <sub>DD</sub>	Power Supply Current, V <sub>DD</sub>		13.0	18	mA	T <sub>A</sub> = +25°C, V <sub>DD</sub> = V <sub>D</sub> = -9V
I <sub>D</sub>	Power Supply Current, V <sub>D</sub>		8.5	12	mA	I <sub>OL</sub> = 0.0mA T <sub>A</sub> = +25°C V <sub>DD</sub> = V <sub>D</sub> = -9V
V <sub>IL</sub>	Input "Low" Voltage	-12		V <sub>CC</sub> -4.5	V	
V <sub>IH</sub>	Input "High" Voltage	V <sub>CC</sub> -2.0		V <sub>CC</sub> +0.3	V	
I <sub>OL1</sub>	Output Sink Current	3.0	6		mA	V <sub>OUT</sub> = +0.45V, T <sub>A</sub> = +25°C
I <sub>OL2</sub>	Output Sink Current	2.0	5		mA	V <sub>OUT</sub> = +0.45V, T <sub>A</sub> = +70°C
I <sub>OL3</sub>	Output Sink Current		6	13	mA	V <sub>OUT</sub> = -0.7 V
I <sub>OH1</sub>	Output Source Current	-3.0	4		mA	V <sub>OUT</sub> = 0.0V, T <sub>A</sub> = +25°C
I <sub>OH2</sub>	Output Source Current	-2.0	3		mA	V <sub>OUT</sub> = 0.0V, T <sub>A</sub> = +70°C
V <sub>OL</sub>	Output "Low" Voltage		-0.7	+0.45	V	I <sub>OL</sub> = 3.0 mA
V <sub>OH</sub>	Output "High" Voltage	+3.5	+4.5		V	I <sub>OH</sub> = -100μA
C <sub>IN</sub>	Input Capacitance (All Input Pins)		7	10	pF	V <sub>IN</sub> = +5.0V f = 1 MHz
C <sub>OUT</sub>	Output Capacitance		7	10	pF	V <sub>OUT</sub> = +5.0 V f = 1 MHz

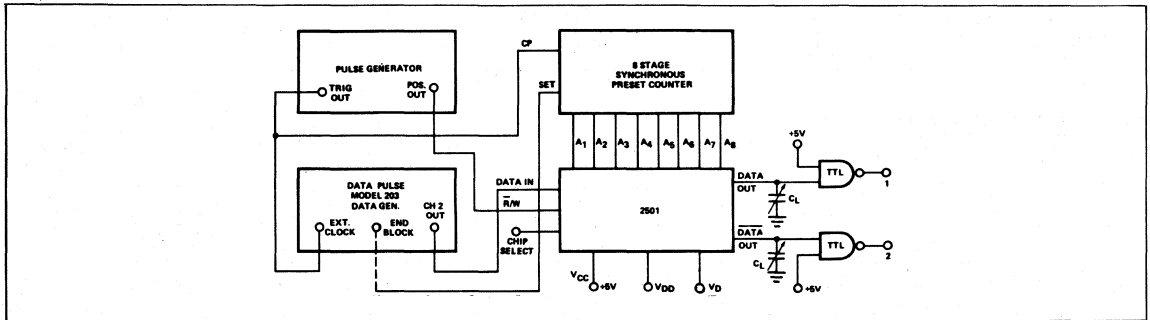
# SIGNETICS 256 X 1 STATIC READ/WRITE RANDOM ACCESS MEMORY ■ 2501

## SWITCHING CHARACTERISTICS

Guaranteed Limits  $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{CC} = +5\text{V}$  (8),  $V_{DD} = V_D = -9\text{V} \pm 5\%$  except as noted.

READ CYCLE			WRITE CYCLE		
SYMBOL	TEST	LIMITS ( $\mu\text{sec}$ ) MAX	SYMBOL	TEST	LIMITS ( $\mu\text{sec}$ ) MIN.
$t_a$	Access Time	1.0 $\mu\text{sec}$	$t_{WD}$	Address to Write Pulse Delay	0.3
			$t_{WP}$	Write Pulse Width	0.4
			$t_W$	Write Time	0.3
			$t_{DO}$	Data-Write Pulse Overlap	0.1

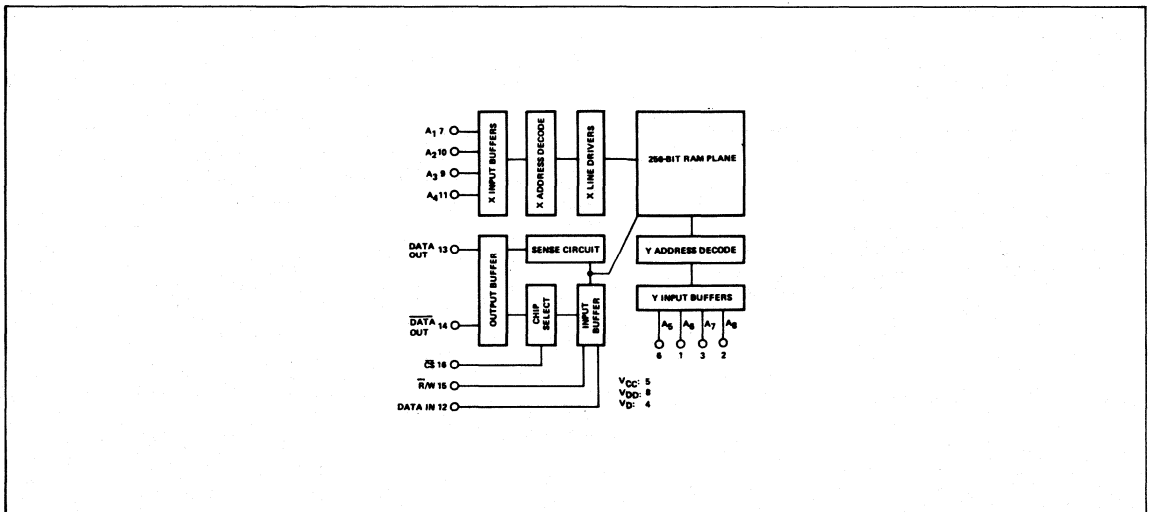
## TEST SETUP FOR SPEED MEASUREMENT



### NOTES:

- Each clock time is split into a Read followed by a Write. Read and Write times can be varied by adjustment of the "delay" and "width" controls of the pulse generator.
- Data generator produces a 256-bit block of data, 32 bits repeated 8 times. "PCM" mode used so data can be changed in 32 bits of the 2501 from one cycle to the next.
- All inputs to the 2501 are standard TTL outputs with  $V_{CC} = +5\text{V} \pm 5\%$ .
- Access time is measured between A1 (least significant address input) and points 1 and 2.

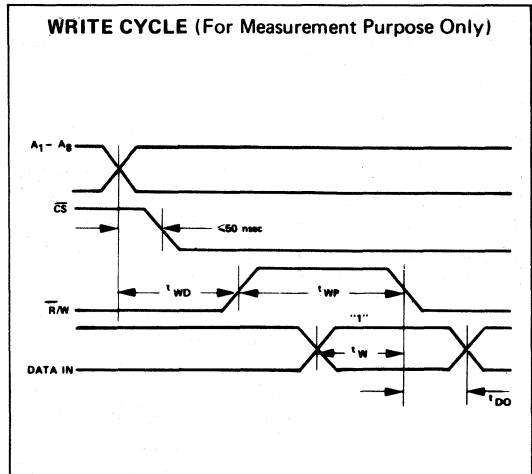
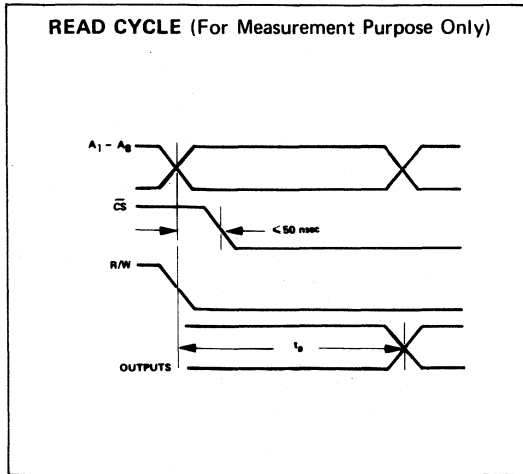
## BLOCK DIAGRAM



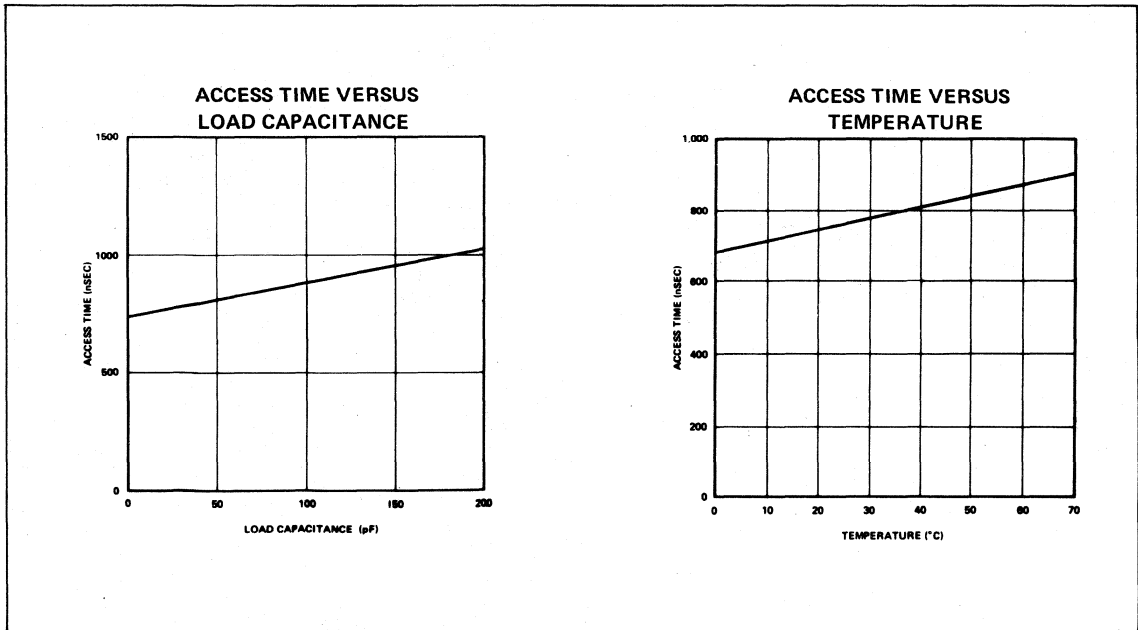


**CONDITIONS OF TEST**

Input pulse amplitudes: 0 to +5V, Input pulse rise and fall times: < 10 nsec. Speed measurements referenced to 1.5V levels. Output load is 1 TTL gate; measurements made at output of TTL gate ( $t_{pd} \leq 10$  nsec)



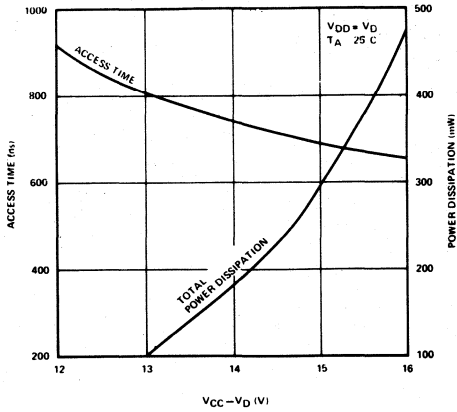
**TYPICAL CHARACTERISTICS**



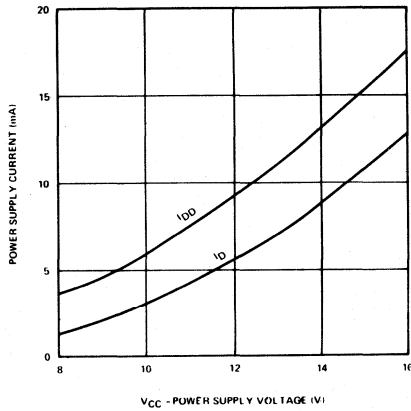
**NOTE:**  
For all typical curves,  $V_{CC} = 5V$ ,  $V_{DD} = V_D = -9V$ ,  $T_A = 25^\circ C$  (unless otherwise noted).

TYPICAL CHARACTERISTICS (Cont'd)

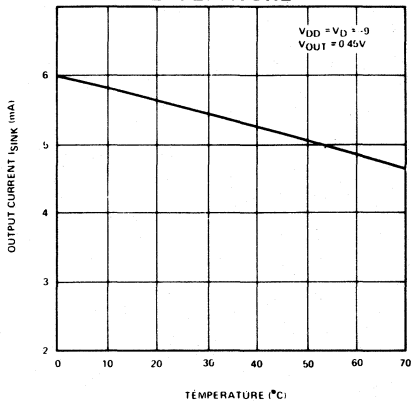
TYPICAL ACCESS TIME AND POWER DISSIPATION VERSUS SINGLE POWER SUPPLY VOLTAGE



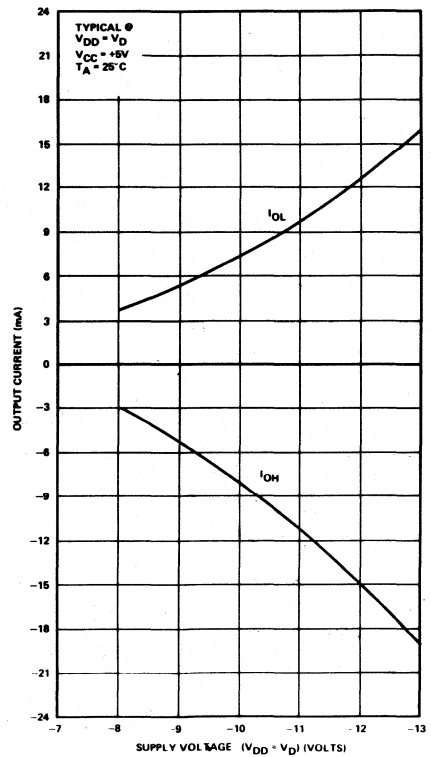
POWER SUPPLY CURRENT VERSUS POWER SUPPLY VOLTAGE



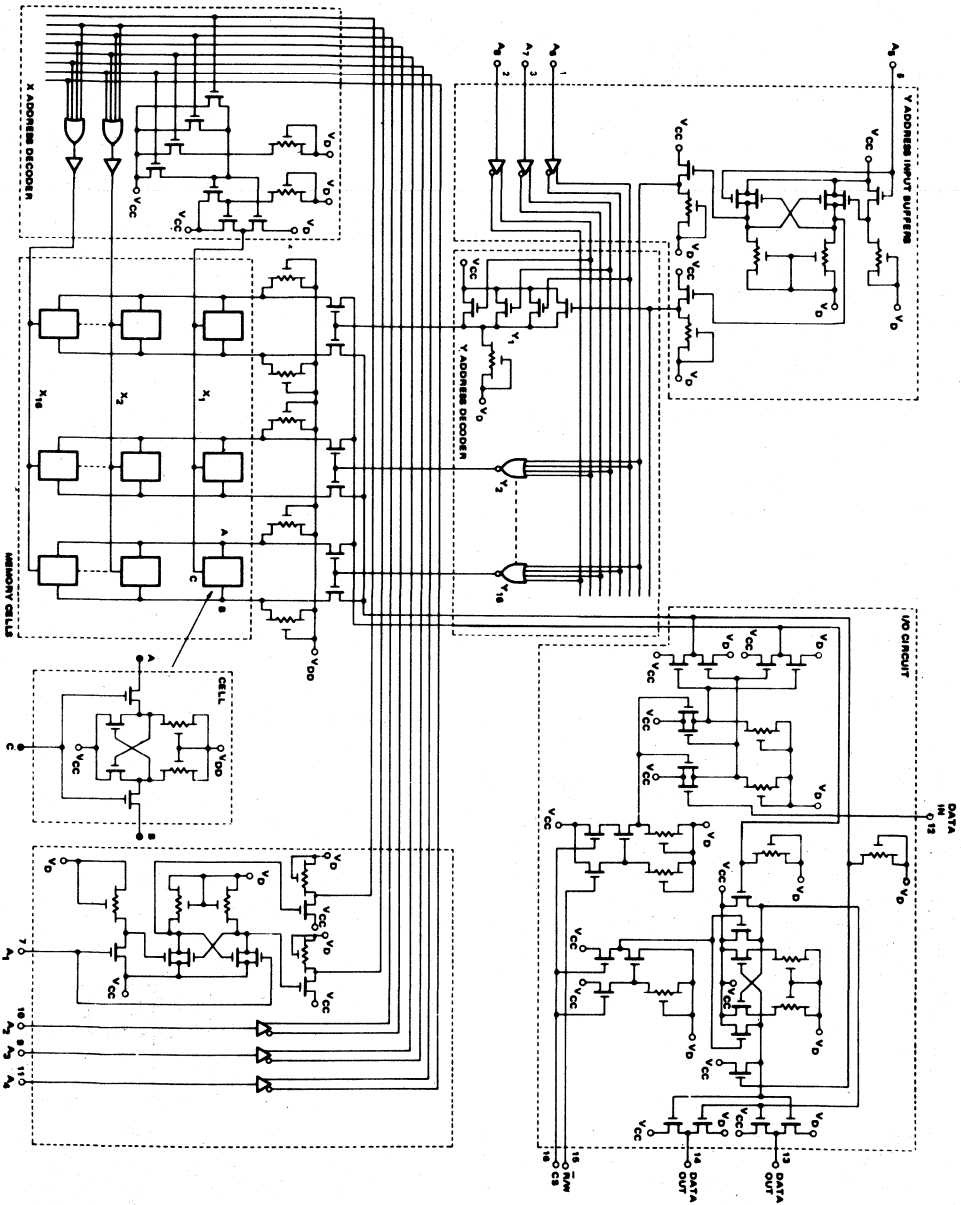
OUTPUT CURRENT VERSUS TEMPERATURE



OUTPUT CURRENT VERSUS SUPPLY VOLTAGE



CIRCUIT SCHEMATIC



Signetics 2501 256 X 1 Static Random Access Memory

### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

The Signetics 25L01-256 x 1 Random Access Memory employs enhancement mode P-channel MOS devices integrated on a single monolithic chip. It is fully decoded, permitting the use of a 16-pin dual in-line package. Complete static operation requires no clocking. The 25L01 is optimized with +5 and -12V supplies.

#### FEATURES

- FULLY DECODED ADDRESSES
- ACCESS TIME: 1.0  $\mu$ s GUARANTEED
- POWER DISSIPATION: 1.7 MW/BIT MAXIMUM
- STANDBY POWER DISSIPATION: 100  $\mu$ W/BIT
- DTL AND TTL COMPATIBLE
- CHIP SELECT AND OUTPUT WIRED-OR CAPABILITY
- STANDARD 16-PIN DIP
- P-MOS SILICON GATE TECHNOLOGY
- $V_{CC} = +5V$ ,  $V_{DD} = V_D = -12V$

#### APPLICATIONS

- SMALL BUFFER STORES
- SMALL CORE MEMORY REPLACEMENT
- BIPOLAR COMPATIBLE DATA STORAGE

#### SILICONE PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process the silicon material over the gate oxide passivates the MOS transistors, and the deposited dielectric material over the silicon gate-oxide-substrate structure provides an ion barrier. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability and demonstrating superior moisture resistance, mechanical shock and ionic contamination barriers.

#### BIPOLAR COMPATIBILITY

All inputs of the 25L01 can be driven directly by standard bipolar integrated circuits (TTL, DTL, etc.). The data output buffers are capable of sinking a minimum of 1.6 mA, sufficient to drive one standard TTL load.

#### POWER DISSIPATION

The maximum power dissipation of 1.7 mW/bit is required only during Read or Write. For standby operation 100  $\mu$ W/bit is obtained by removing  $V_D$  and reducing  $V_{DD}$  to -8.0V.

Removal of  $V_D$  alone will cut power dissipation by a factor of almost 3.

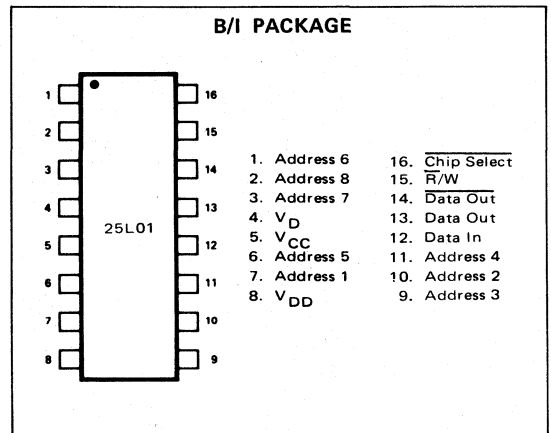
#### TRI-STATE OUTPUT

The outputs of the 25L01 are effectively open circuited when the device is not selected (logic 1 on chip select). This feature allows OR-tying for memory expansion.

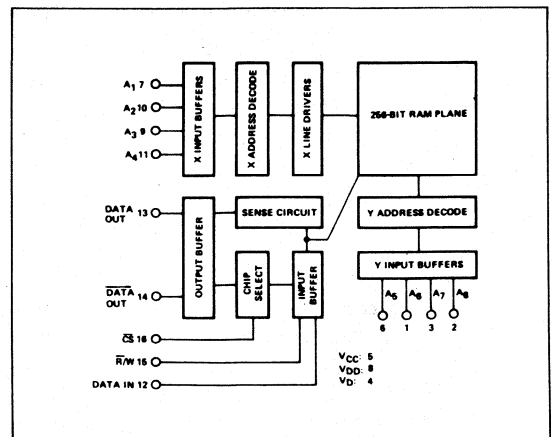
#### PART IDENTIFICATION TABLE

TYPE	PACKAGE	OP. TEMP. RANGE
25L01B	16-pin Silicone DIP	0°C to +70°C
25L01I	16-pin Ceramic DIP	0°C to +70°C

#### PIN CONFIGURATION (Top View)



#### BLOCK DIAGRAM



**MAXIMUM GUARANTEED RATINGS (1)**

NOTES:

Operating Temperature	0°C to +70°C
Storage Temperature	-65°C to +150°C
All Input or Output Voltages with Respect to the Most Positive Supply Voltage, VCC	+0.3V to -20V
Supply Voltages V <sub>DD</sub> and V <sub>D</sub> with Respect to VCC	-18V
Power Dissipation at T <sub>A</sub> = 25°C "B" pkg.	640 mW
"I" pkg.	800 mW

1. Stresses above those listed under "Maximum Guaranteed Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device of these or any other condition above those indicated in the operation sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W junction to ambient ("B" pkg.) ("I" pkg., 100°C/W).
3. All inputs protected against static charge.
4. Parameter valid over operating temperature range unless otherwise specified.
5. All voltage measurements are referenced to ground.
6. Manufacturer reserves the right to make design and process changes and improvements.
7. Typical values are at +25°C and nominal supply voltages.

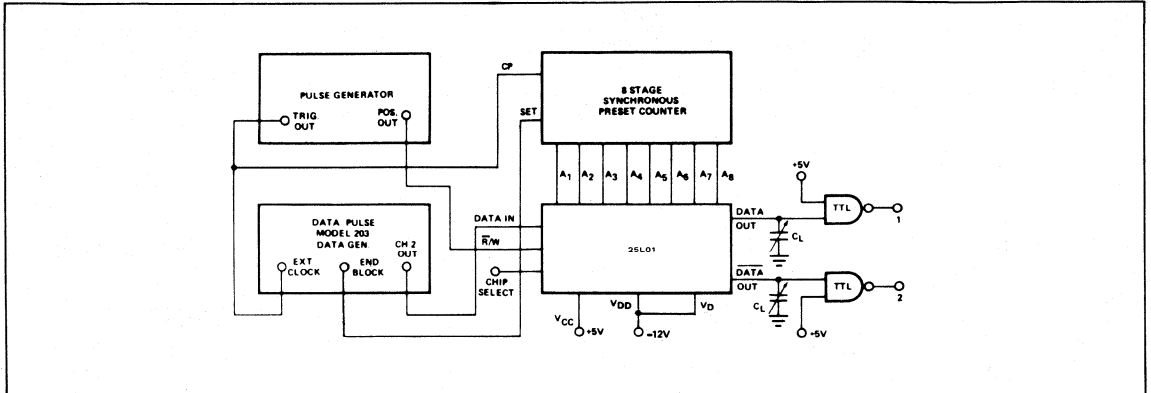
**DC CHARACTERISTICS** (T<sub>A</sub> = 0°C to 70°C, V<sub>CC</sub> = +5V ± 5%, V<sub>DD</sub> = V<sub>D</sub> = -12V ± 5% unless otherwise specified. See notes above).

SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current (All Input Pins)		<1.0	500	nA	V <sub>IN</sub> = 0.0V; T <sub>A</sub> = +25°C
I <sub>LO</sub>	Output Leakage Current		<1.0	1000	nA	V <sub>OUT</sub> = 0.0V, Chip Select Input = +3.3V, T <sub>A</sub> = +25°C
I <sub>DD</sub>	Power Supply Current, V <sub>DD</sub>		5	9	mA	T <sub>A</sub> = +25°C
I <sub>D</sub>	Power Supply Current, V <sub>D</sub>		11	16	mA	I <sub>OL</sub> = 0.0 mA T <sub>A</sub> = +25°C
V <sub>IL</sub>	Input "Low" Voltage	-12		V <sub>CC</sub> -4.5	V	
V <sub>IH</sub>	Input "High" Voltage	V <sub>CC</sub> -2.0		V <sub>CC</sub> +0.3	V	
I <sub>OL1</sub>	Output Sink Current	3.0	6		mA	V <sub>OUT</sub> = +0.45V, T <sub>A</sub> = +25°C
I <sub>OL2</sub>	Output Sink Current	2.0	5		mA	V <sub>OUT</sub> = +0.45V, T <sub>A</sub> = +70°C
I <sub>OL3</sub>	Output Sink Current		6	13	mA	V <sub>OUT</sub> = -0.7 V
I <sub>OH1</sub>	Output Source Current	-3.0	4		mA	V <sub>OUT</sub> = 0.0V, T <sub>A</sub> = +25°C
I <sub>OH2</sub>	Output Source Current	-2.0	3		mA	V <sub>OUT</sub> = 0.0V, T <sub>A</sub> = +70°C
V <sub>OL</sub>	Output "Low" Voltage		-0.7	+0.45	V	I <sub>OL</sub> = 3.0 mA
V <sub>OH</sub>	Output "High" Voltage	+3.5	+4.5		V	I <sub>OH</sub> = -100µA
C <sub>IN</sub>	Input Capacitance (All Input Pins)		7	10	pF	V <sub>IN</sub> = +5.0V f = 1 MHz
C <sub>OUT</sub>	Output Capacitance		7	10	pF	V <sub>OUT</sub> = +5.0 V f = 1 MHz

**SWITCHING CHARACTERISTICS** Guaranteed Limits  $T_A = 0$  to  $+70^\circ\text{C}$ ,  $V_{CC} = +5\text{V} \pm 5\%$ ,  $V_{DD} = V_D = -12\text{V} \pm 5\%$

READ CYCLE			WRITE CYCLE		
SYMBOL	TEST	LIMITS ( $\mu\text{sec}$ ) MAX	SYMBOL	TEST	LIMITS ( $\mu\text{sec}$ ) MIN.
$t_a$	Access Time	1 $\mu\text{sec}$	$t_{WD}$	Address to Write Pulse Delay	0.3
			$t_{WP}$	Write Pulse Width	0.4
			$t_W$	Write Time	0.3
			$t_{DO}$	Data-Write Pulse Overlap	0.1

**TEST SETUP FOR SPEED MEASUREMENT**



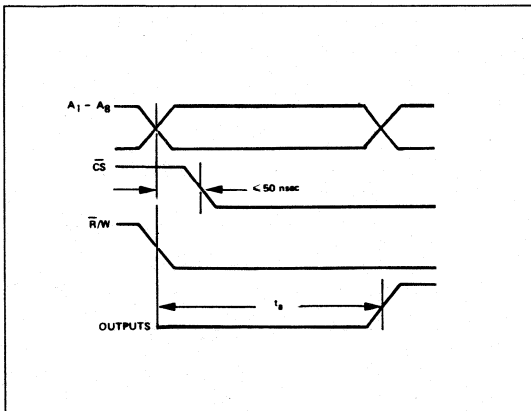
**NOTES:**

- Each clock time is split into a Read followed by a Write. Read and Write times can be varied by adjustment of the "delay" and "width" controls of the pulse generator.
- Data generator produces a 256-bit block of data, 32 bits repeated 8 times. "PCM" mode used so data can be changed in 32 bits of the 25L01 from one cycle to the next.
- All inputs to the 25L01 are standard TTL outputs with  $V_{CC} = +5\text{V} \pm 5\%$ .
- Access time is measured between A1 (least significant address input) and points 1 and 2.

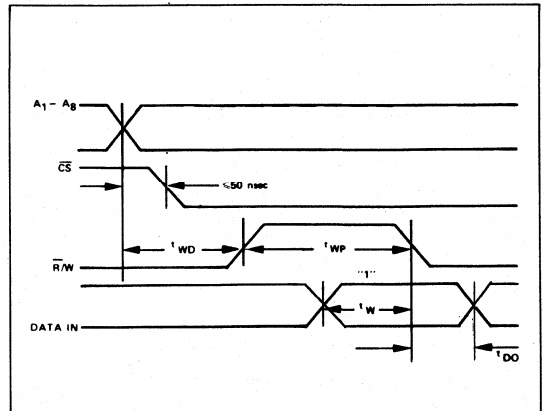
**CONDITIONS OF TEST**

Input pulse amplitudes: 0 to +5V, Input pulse rise and fall times:  $< 10$  nsec. Speed measurements referenced to 1.5V levels. Output load is 1 TTL gate; measurements made at output of TTL gate ( $t_{pd} \leq 10$  nsec).

**READ CYCLE (For Measurement Purpose Only)**



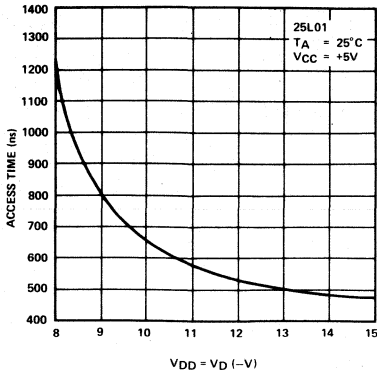
**WRITE CYCLE (For Measurement Purpose Only)**



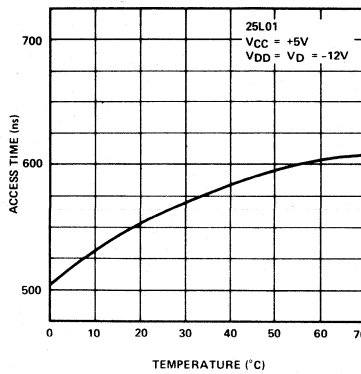
**APPLICATION INFORMATION:** Reference 2501 specifications.

TYPICAL CHARACTERISTIC CURVES

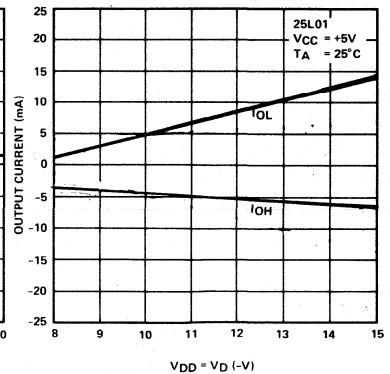
ACCESS TIME VERSUS SUPPLY VOLTAGE



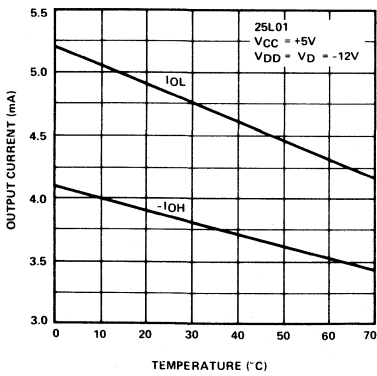
ACCESS TIME VERSUS TEMPERATURE



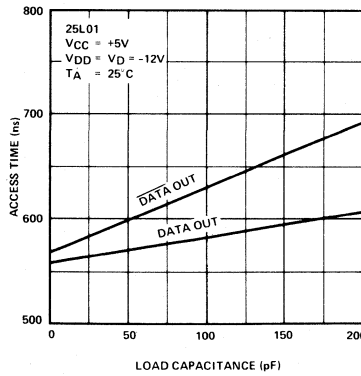
OUTPUT CURRENT VERSUS SUPPLY VOLTAGE



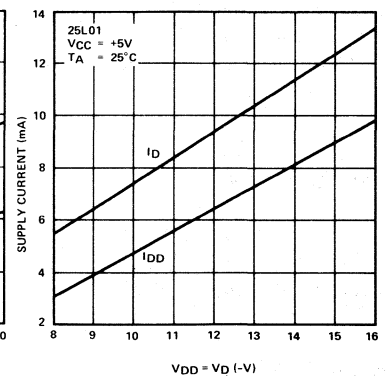
OUTPUT CURRENT VERSUS TEMPERATURE



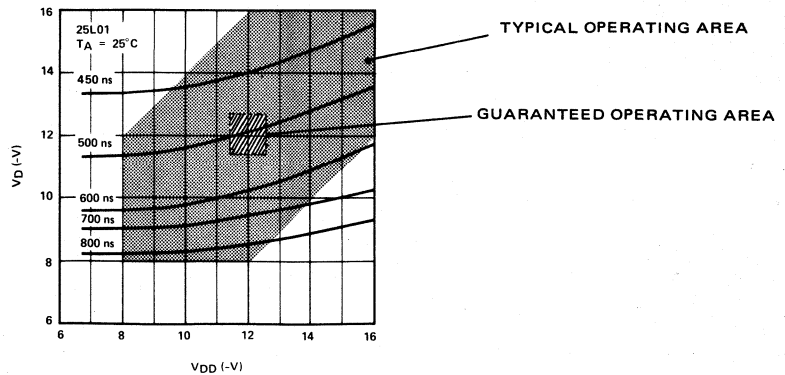
ACCESS TIME VERSUS LOAD CAPACITANCE



POWER SUPPLY CURRENT VERSUS SUPPLY VOLTAGE



ACCESS TIME VERSUS SUPPLY VOLTAGES



#### DESCRIPTION

These Signetics 2500 Series 1024-bit multiplexed dynamic shift registers consist of enhancement mode P-channel MOS devices integrated on a single monolithic chip. Due to on-chip multiplexing, the data rate is twice the clock rate.

#### FEATURES

- 10 MHz TYPICAL DATA RATE
- THREE CONFIGURATIONS—QUAD 256, DUAL 512, SINGLE 1024
- LOW POWER DISSIPATION: 40  $\mu$ W/BIT AT 1 MHz DATA RATE
- TTL, DTL COMPATIBLE
- STANDARD PACKAGES
- SIGNETICS P-MOS SILICON GATE PROCESS AND SILICONE PACKAGING TECHNOLOGIES

#### APPLICATIONS

LOW COST SEQUENTIAL ACCESS MEMORIES  
LOW COST BUFFER MEMORIES  
CRT REFRESH MEMORIES  
DELAY LINE MEMORY REPLACEMENT

#### PROCESS TECHNOLOGY

Use of low threshold *silicon gate technology* allows high speed (10 MHz typical) while reducing power dissipation and clock input capacitance dramatically as compared to metal gate technologies.

The use of low voltage circuitry minimizes power dissipation and facilitates interfacing with bipolar integrated circuits.

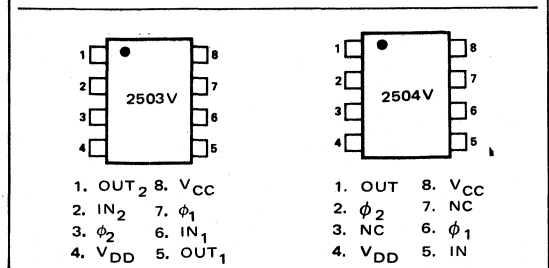
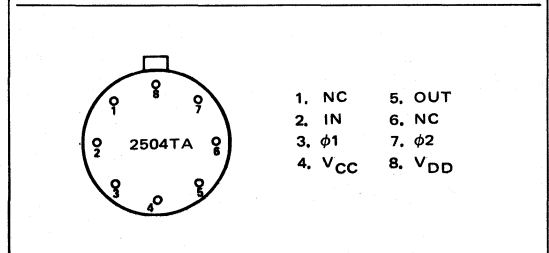
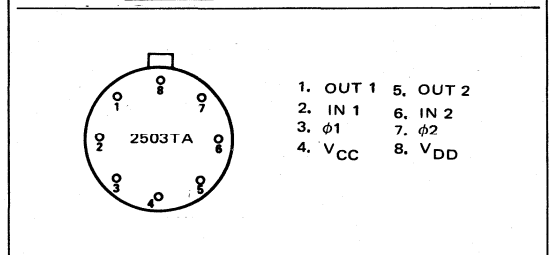
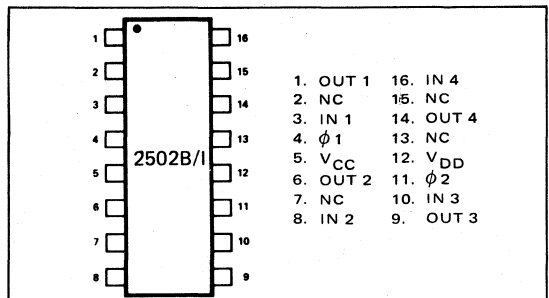
#### SILICONE PACKAGING

Low cost silicone DIP packaging is implemented, and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process, the silicon material over the gate oxide passivates the MOS transistors, and the deposited dielectric material over the silicon gate-oxide-substrate structure provides an ion barrier. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability and demonstrating superior moisture resistance, mechanical shock and ionic contamination barriers.

#### BIPOLAR COMPATIBILITY

The data inputs of these registers can be driven directly by standard bipolar integrated (TTL, DTL, etc.) or by MOS circuits. The bare drain output stage provides driving capability for both MOS and bipolar integrated circuits (one standard TTL load).

#### PIN CONFIGURATIONS (Top View)





# SIGNETICS 1024-BIT CAPACITY MULTIPLEXED DYNAMIC SHIFT REGISTERS ■ 2502/3/4

## PART IDENTIFICATION TABLE

TYPE	FUNCTION	PACKAGE
2502B	Quad 256-bit	16-Pin Silicone DIP
2502I	Quad 256-bit	16-Pin Ceramic DIP
2503TA	Dual 512-bit	TO-99
2503V	Dual 512-bit	8-Pin DIP
2504TA	Single 1024-bit	TO-99
2504V	Single 1024-bit	8-Pin DIP

## NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W (TA and V package) or 125°C/W (B package).
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserving the right to make design and process changes and improvements.
- Typical values at +25°C and nominal supply voltages.
- Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.
- When cascading use 140nc minimum pulse width to allow data set-up time for driver register.

## MAXIMUM SIGNETICS GUARANTEED RATINGS<sup>(1)</sup>

Operating Ambient Temperature <sup>(2)</sup>	0°C to +70°C
Storage Temperature	-65°C to +150°C
Power Dissipation <sup>(2)</sup> at T <sub>A</sub> = 70°C	
TA and V Package	535mW
B Package	640mW
Data and Clock Input Voltages and Supply Voltages with respect to V <sub>CC</sub> <sup>(3)</sup>	+0.3V to -20V

## DC CHARACTERISTICS

T<sub>A</sub> = 0°C to +70°C; V<sub>DD</sub> = -5V ±5%; V<sub>CC</sub> = +5V(8) unless otherwise noted. (See Notes 4,5,6,7).

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current		10	500	nA	V <sub>IN</sub> = V <sub>CC</sub> to V <sub>DD</sub> , T <sub>A</sub> = 25°C
I <sub>LO</sub>	Output Leakage Current		10	1000	nA	V <sub>φ1</sub> = V <sub>φ2</sub> = -10V V <sub>OUT</sub> = 0.0V, T <sub>A</sub> = 25°C
I <sub>LC</sub>	Clock Leakage Current		10	1000	nA	V <sub>ILC</sub> = -10V, T <sub>A</sub> = 25°C
I <sub>DD</sub>	Power Supply Current		15	25	mA	Outputs at logic "0", 4 MHz data rate, φ1 = φ2 = 85ns continuous operation, V <sub>ILC</sub> = -12V T <sub>A</sub> = 25°C
V <sub>IL</sub>	Input "Low" Voltage			+0.6	V	See Note 8
V <sub>IH</sub>	Input "High" Voltage	+3.4		5.3	V	See Note 8
V <sub>IHC</sub>	Clock Input "High" Voltage	4.0		5.3	V	
V <sub>ILC</sub>	Clock Input "Low" Voltage	-10		-12	V	

# SIGNETICS 1024-BIT CAPACITY MULTIPLEXED DYNAMIC SHIFT REGISTERS ■ 2502/3/4

## AC CHARACTERISTICS

$T_A = 25^\circ\text{C}$ ,  $V_{DD} = -5\text{V} \pm 5\%$ ;  $V_{CC} = +5\text{V}$  (8);  $V_{ILC} = -11\text{V}$ , (See notes 4, 5, 6, 7).

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
Frequency	Clock Rep Rate	0.0005		4	MHz	
Frequency	Data Rep Rate	0.001		8	MHz	
$\phi_{pw}$	Clock Pulse Width (9)	85			ns	See note 9
$\phi_d$	Clock Pulse Delay	10			ns	
$t_r, t_f$	Clock Pulse Transition	10		1000	ns	
$t_w$	Data Write Time (Setup)	50			ns	
$t_{DO}$	Data in Overlap	10			ns	
$t_{a+}$	Data Out			90	ns	
$C_{IN}$	Input Capacitance	2.5		5	pF	@ 1 MHz 25 mV p-p
$C_{OUT}$	Output Capacitance	2.5		5	pF	@ 1 MHz 25 mV p-p
$C_\phi$	Clock Capacitance	130		150	pF	@ 1 MHz 25 mV p-p
$V_{OL}$	Output "Low" Voltage		-0.3		V	$R_L = 3k$ , depends on $R_L$ and TTL Gate
$V_{OH1}$	Output "High" Voltage Driving MOS	3.6	4.0		V	$R_L = 5.6k$
$V_{OH2}$	Output "High" Voltage Driving TTL	3.0	3.5		V	$R_L = 3k$

## MULTIPLEXED 4-BIT MOS SHIFT REGISTER

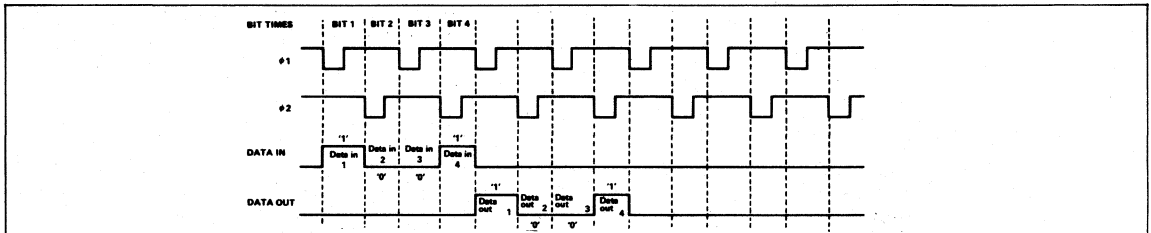
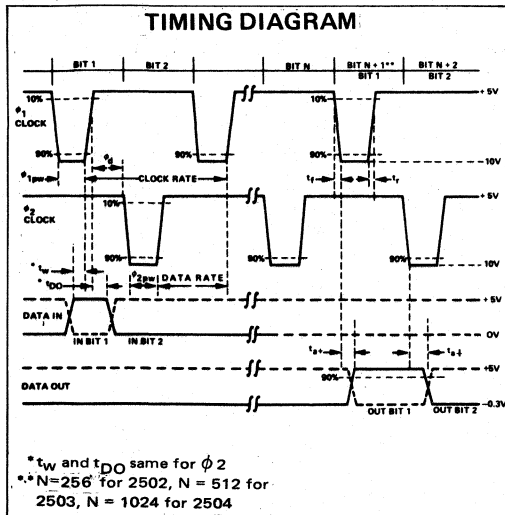


Figure 1

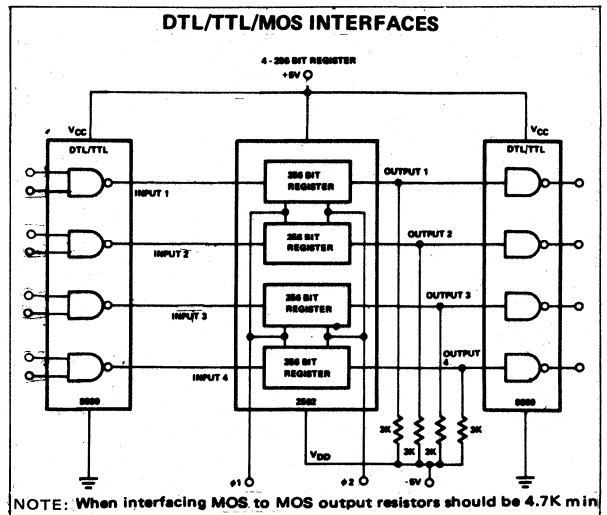
Figure 1 is a simplified illustration of the timing of a 4-bit multiplexed register showing input output relationships with respect to the clock. If data enters the register at  $\phi 1$  time, it exits at  $\phi 1$  time, (beginning on  $\phi 1$ 's negative going edge and ending on the succeeding  $\phi 2$ 's negative going edge).

## CONDITIONS OF TEST

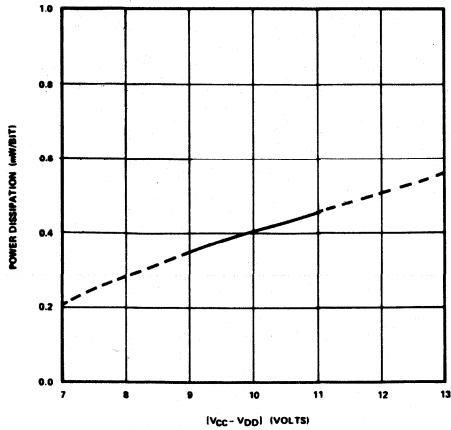
Input rise and fall times: 10nsec. Output load is 1 TTL gate.



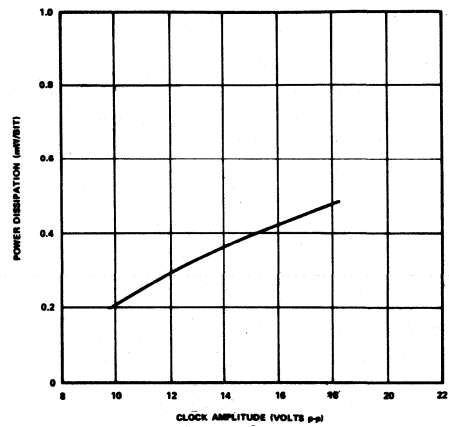
## APPLICATIONS INFORMATION



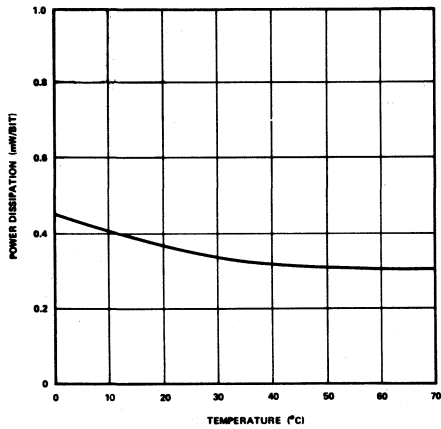
**POWER DISSIPATION/BIT  
VERSUS SUPPLY VOLTAGE**



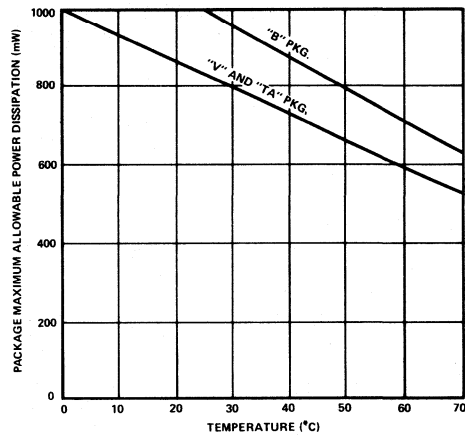
**POWER DISSIPATION/BIT  
VERSUS CLOCK AMPLITUDE**



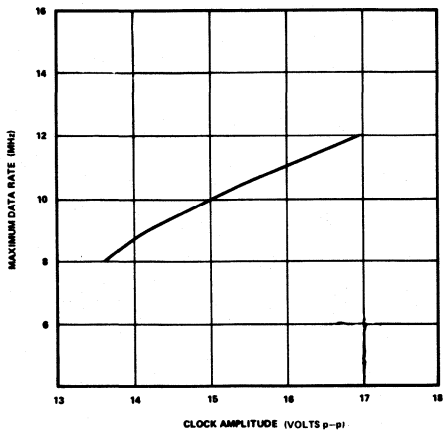
**POWER DISSIPATION/BIT  
VERSUS TEMPERATURE**



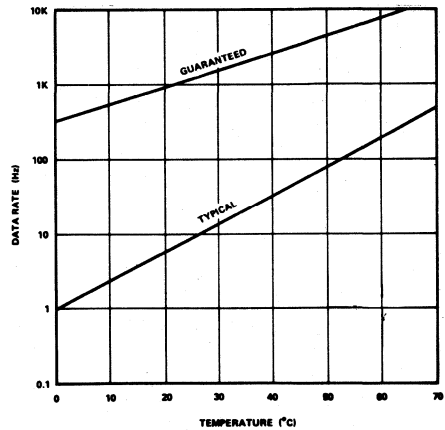
**MAXIMUM ALLOWABLE POWER DISSIPATION  
VERSUS AMBIENT TEMPERATURE**



**CLOCK AMPLITUDE  $V_{\phi}$   
VERSUS MAXIMUM DATA RATE**

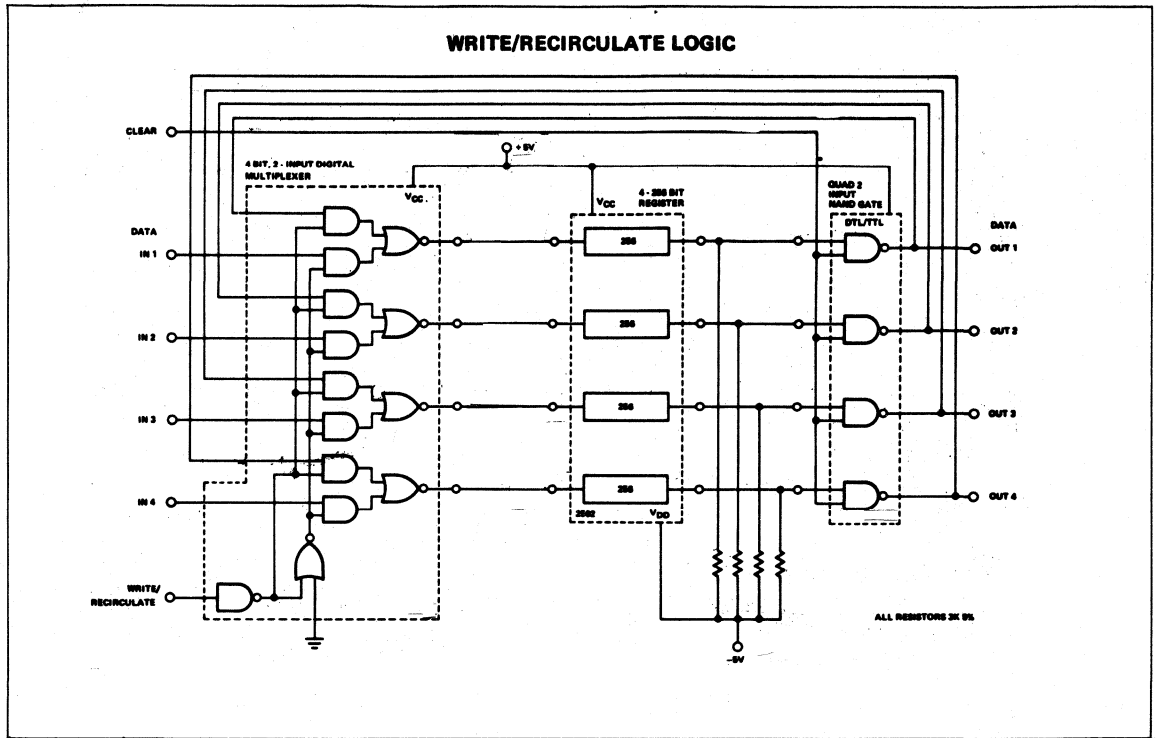


**MINIMUM OPERATING DATA RATE  
VERSUS TEMPERATURE**

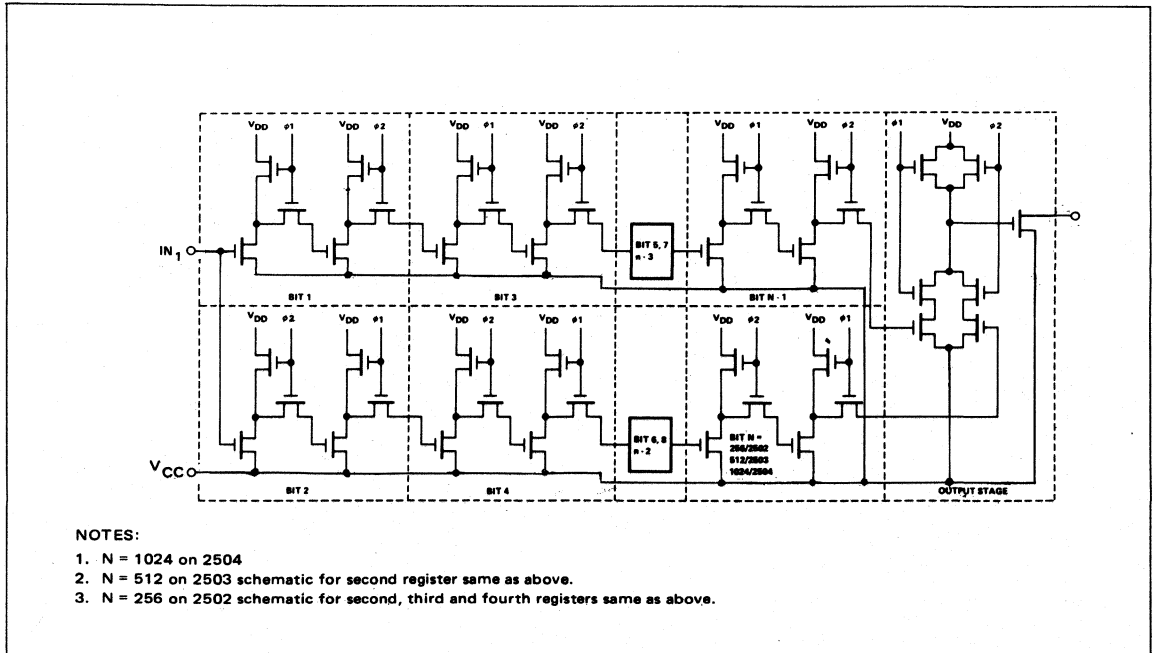


NOTE: Conditions for Typical Curves;  $V_{CC} = +5V, V_{DD} = -5V, \phi_{1PW}$  and  $\phi_{2PW} = 85ns, V_{\phi} = -11V, T_A = 25^{\circ}C, f_{DATA} = 10MHz$  unless otherwise noted.

APPLICATIONS (Cont'd)



CIRCUIT SCHEMATIC



### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

These Signetics 2500 Series 512 and 1024 bit recirculating dynamic shift registers consist of enhancement mode P-channel MOS devices integrated on a single monolithic chip. Internal recirculation logic plus write and read controls, together with two chip select controls are included on the chip.

#### FEATURES

- HIGH FREQUENCY OPERATION—3 MHz TYPICAL CLOCK RATE
- SINGLE 512, SINGLE 1024
- TTL, DTL COMPATIBLE
- 2-CHIP SELECT CONTROLS FOR XY MATRIX SELECTION
- WRITE AND READ CONTROLS INCLUDED
- LOW POWER DISSIPATION—150 $\mu$ W/bit at 1 MHz
- LOW CLOCK CAPACITANCE—80pF for 512, 160pF for 1024 Bits
- +5, -5V POWER SUPPLIES
- STANDARD PACKAGE—10 LEAD TO-100
- SIGNETICS P-MOS SILICON GATE PROCESS TECHNOLOGY

#### APPLICATIONS

FAST ACCESS SWAPPING MEMORY SYSTEMS  
 LOW COST SEQUENTIAL ACCESS MEMORIES  
 LOW COST BUFFER MEMORIES  
 CRT REFRESH MEMORIES  
 DELAY LINE MEMORY REPLACEMENT  
 DRUM MEMORY REPLACEMENT

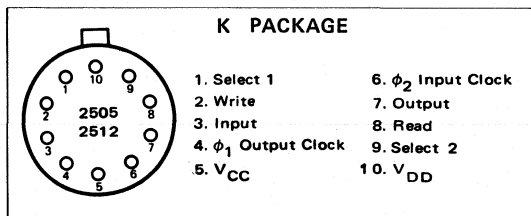
#### PROCESS TECHNOLOGY

Use of low threshold *silicon gate technology* allows high speed (3MHz typical) while reducing power dissipation and clock input capacitance dramatically as compared to other technologies. The use of low voltage circuitry minimizes power dissipation and facilitates interfacing with bipolar integrated circuits.

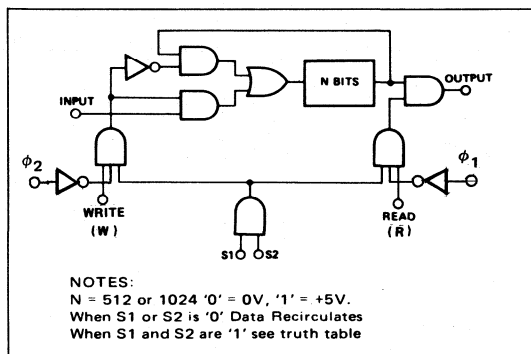
#### BIPOLAR COMPATIBILITY

The signal inputs of these registers can be driven directly by standard bipolar integrated (TTL, DTL, etc.) or by MOS circuits. The bare drain output stage provides driving capability for both MOS and bipolar integrated circuits (one standard TTL load).

#### PIN CONFIGURATION<sup>1</sup> (Top View)



#### BLOCK DIAGRAM



#### TRUTH TABLE

WRITE	READ	FUNCTION
0	0	Recirculate, Output is '0'
0	1	Recirculate, Output is Data
1	0	Write Mode, Output is '0'
1	1	Read/Write, Output is Data

#### PART IDENTIFICATION TABLE

PART NO.	BIT LENGTH	PACKAGE
2505K	512	10 pin TO - 100
2512K	1024	10 pin TO - 100

#### MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature (2) 0°C to +70°C  
 Storage Temperature -65°C to +150°C  
 Power Dissipation (2) 535mW@ $T_A > 70^\circ\text{C}$   
 Data and Clock Input Voltages and Supply Voltages with respect to  $V_{CC}$  +0.3V to -20V

# SIGNETICS 512 AND 1024-BIT RECIRCULATING DYNAMIC SHIFT REGISTERS ■ 2505, 2512

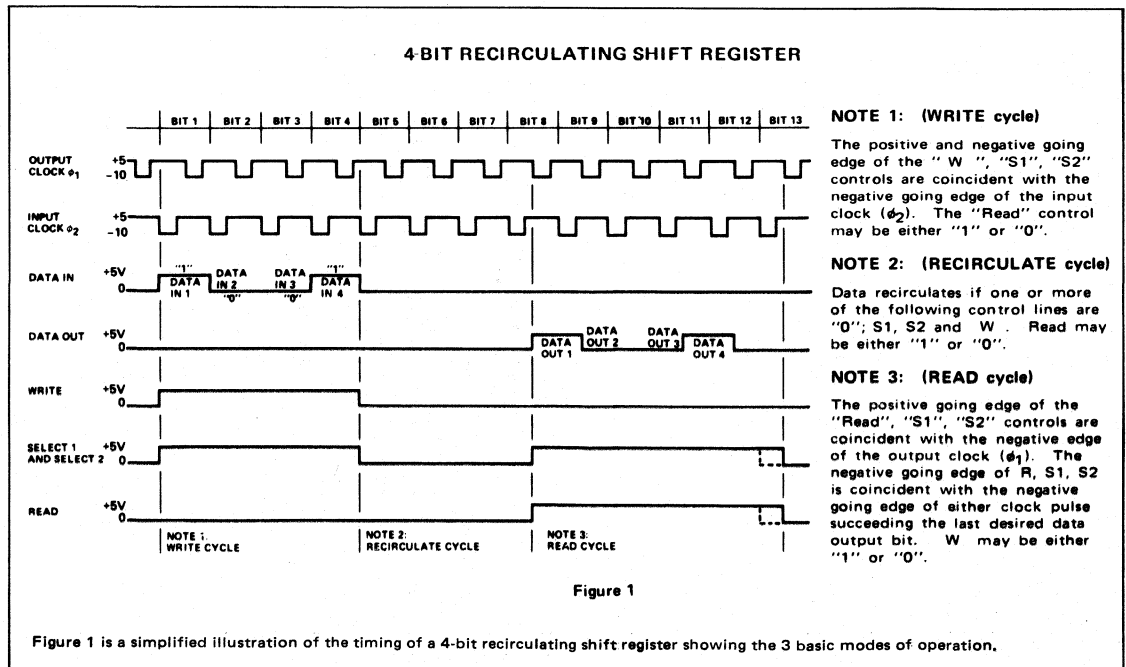
## NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W junction to ambient.
- All inputs are protected against static charge.
- See "Minimum Operating Frequency" graph for low limits on data rep. rate.
- Parameters are valid over operating temperature range unless otherwise specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and nominal supply voltages.
- Guaranteed input levels are stated for worst case conditions including a ±5% variation in  $V_{CC}$  and a temperature variation of 0°C to +70°C. Actual input requirements with respect to  $V_{CC}$  are  $V_{IH} = V_{CC} - 1.85V$  and  $V_{IL} = V_{CC} - 4.15V$ .
- $V_{OL}$  is a function of the input characteristics of the driven TTL/DTL gate  $I_{O1}$  and  $V_{CLAMP}$  and the value of the pull-down resistor ( $R_L$ ).

DC CHARACTERISTICS  $T_A = 0^\circ C$  to  $+70^\circ C$ ;  $V_{CC} = +5V \pm 5\%$ ;  $V_{DD} = -5V \pm 5\%$  unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$I_{LI}$	Input Load Current		10	500	nA	$V_{IN} = -5.5V$ ; $T_A = 25^\circ C$
$I_{LO}$	Output Leakage Current		10	1000	nA	$V_{\phi 1} = V_{\phi 2} = -12V$ , $V_{DD} = -5V$ ; $V_{OUT} = -5.5V$ ; $T_A = 25^\circ C$
$I_{LC}$	Clock Leakage Current		10	1000	nA	$V_{ILC} = -12V$ ; $T_A = 25^\circ C$
$I_{DD}$	Power Supply Current: 2505		15	25	mA	Continuous Operation; $\phi = 150ns$ , 1MHz $V_{ILC} = -12V$ ; $T_A = 25^\circ C$ $V_{DD} = -5.5V$
		2512		25	35	
$V_{IL}$	Input "Low" Voltage	-5.0		+0.6	V	See Note 9
$V_{IH}$	Input "High" Voltage	+3.4		5.3	V	See Note 9
$V_{ILC}$	Clock Input "Low" Voltage	-12.0		10.0	V	
$V_{IHC}$	Clock Input "High" Voltage	4.0		5.3	V	

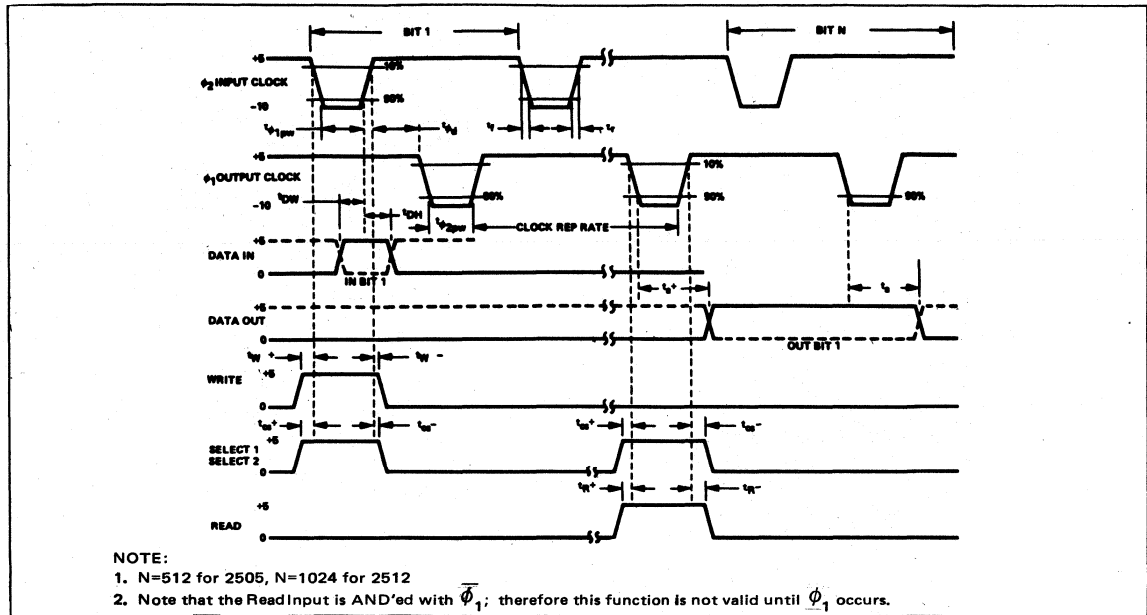
## EXAMPLE TIMING DIAGRAM



CONDITIONS OF TEST

Input rise and fall times: 10 nsec Output load is 1 TTL gate

TIMING DIAGRAM

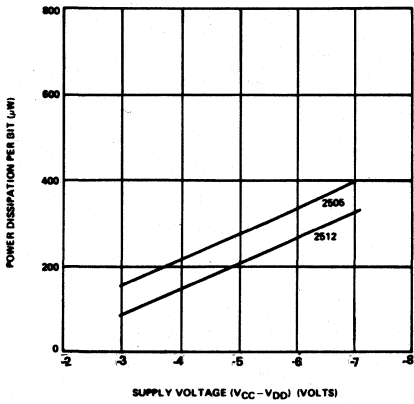


AC CHARACTERISTICS  $T_A = +25^\circ C$   $V_{CC} = +5V$  (9);  $V_{DD} = -5V \pm 5\%$ ;  $V_{ILC} = -11V$

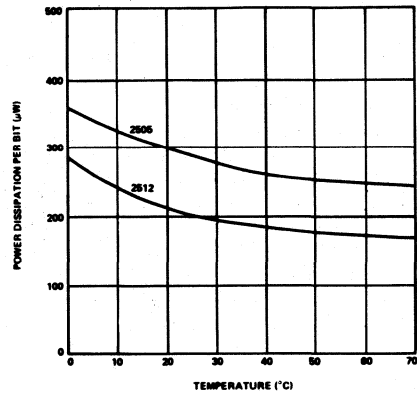
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
Frequency	Clock Data Rep Rate	.0005 (Note 4)	3	2.5	MHz	$W = R = V_{CC}$
$t_{ppw}$	Clock Pulse Width	180			nsec	
$t_{pd}$	Clock Pulse Delay	10			nsec	
$t_r, t_f$	Clock Pulse Transition			1	$\mu$ sec	
$t_{DW}$	Data Write (Setup) Time	150			nsec	
$t_{DH}$	Data to Clock Hold Time	10			nsec	
$t_{a+}, t_{a-}$	Clock to Data Out Delay			100	nsec	
$t_{R-}; t_{CS-}; t_{W-}$	Clock to "Read" or "Chip Select" or "Write" Timing	0			nsec	
$t_{R+}; t_{CS+}; t_{W+}$	Clock to "Read" or "Chip Select" or "Write" Timing	0			nsec	
$C_{in}$	Input Capacitance			5	pF	1 MHz; $V_I = V_{CC}$ ; $V_{AC} = 25mV_{p-p}$
$C_{out}$	Output Capacitance			5	pF	1 MHz; $V_O = V_{CC}$ ; $V_{AC} = 25mV_{p-p}$
$C_\phi$	Clock Capacitance			50 100	pF pF	1 MHz; $V = V_{CC}$ ; $V_{AC} = 25mV_{p-p}$
$V_{OL}$	Output "Low" Voltage		-1.0		V	$R_L = 3.0K$ ; 1 TTL Load ( $I_L = 1.6mA$ ) Note 10
$V_{OH1}$	Output "High" Voltage Driving 1 TTL Load	2.4	3.5		V	$R_L = 3.0K$ ; 1 TTL Load ( $I_L = 100\mu A$ )
$V_{OH2}$	Output "High" Voltage Driving MOS	3.6	4.0		V	$R_L = 5.6K$ ; $C_L = 10 pF$

CHARACTERISTICS CURVES

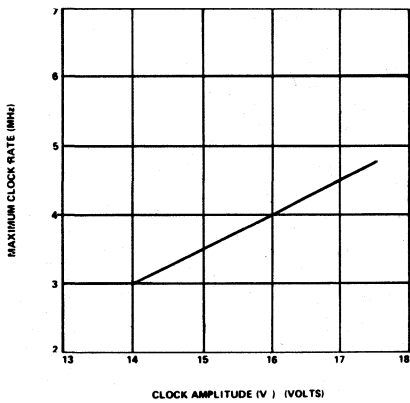
POWER DISSIPATION/BIT  
VERSUS SUPPLY VOLTAGE



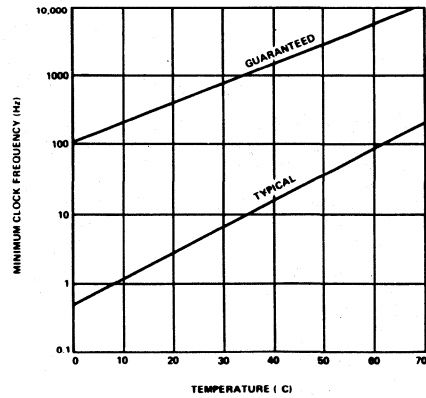
POWER DISSIPATION/BIT  
VERSUS TEMPERATURE



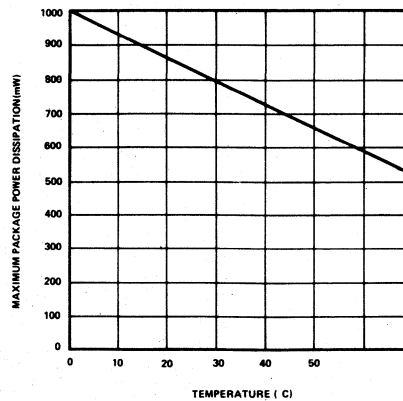
MAXIMUM CLOCK RATE  
VERSUS CLOCK AMPLITUDE



MINIMUM OPERATING  
CLOCK FREQUENCY



MAXIMUM PACKAGE POWER DISSIPATION  
VERSUS TEMPERATURE



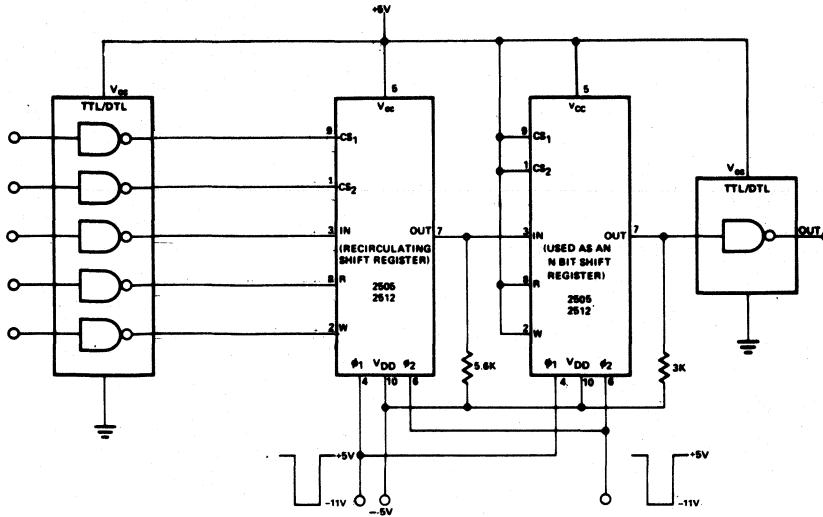
NOTE:

Conditions for Typical Curves = V<sub>CC</sub>=+5V, V<sub>DD</sub>=-5V, Clock Duty Cycle=35%, f<sub>CLK</sub>=2.5MHz, V<sub>φP-P</sub>=16V, φ<sub>PW</sub>=180ns, T<sub>A</sub>=25°C unless otherwise noted

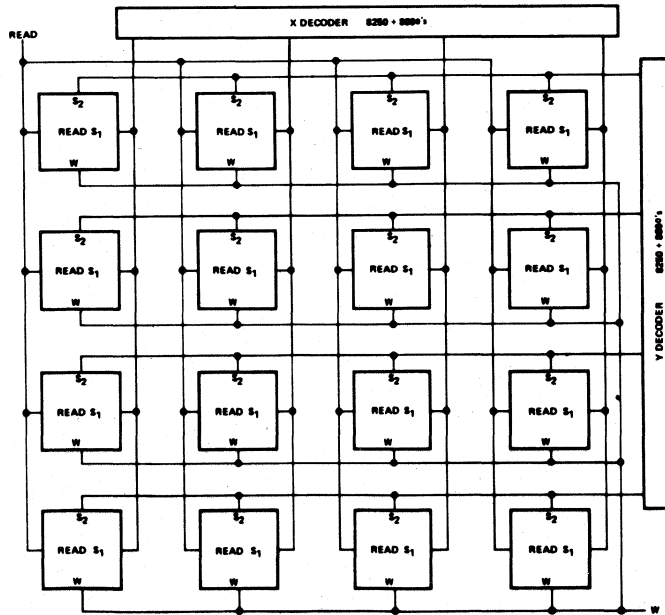


APPLICATIONS DATA

TTL/DTL/MOS INTERFACES



MATRIX CHIP SELECT LOGIC

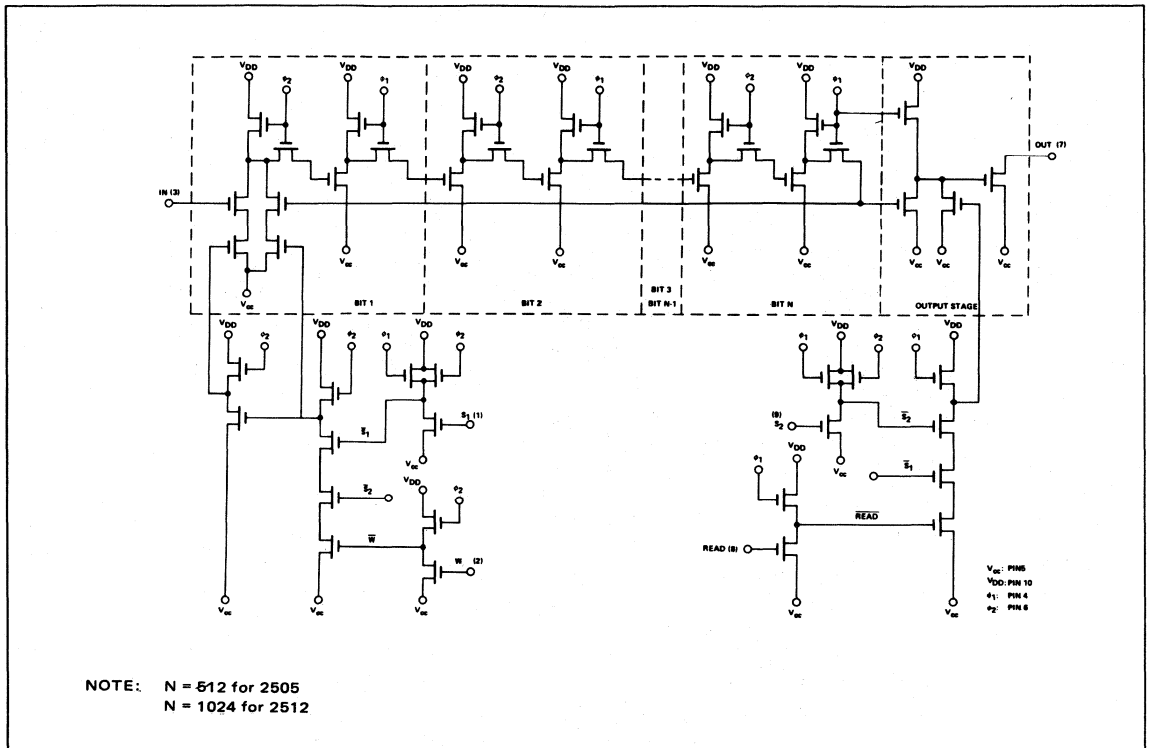


NOTES:

1. Outputs common for each plane
2. All inputs common for each plane
3. All  $\phi_1$ 's common
4. All  $\phi_2$ 's common
5. All  $V_{CC}$  common
6. All  $V_{DD}$  common

**SIGNETICS 512 AND 1024-BIT RECIRCULATING DYNAMIC SHIFT REGISTERS ■ 2505, 2512**

**CIRCUIT SCHEMATIC**



#### DESCRIPTION

These Signetics 2500 Series Dual 50, 100, and 200 bit recirculating static shift registers consist of enhancement mode P-channel silicon gate MOS devices integrated on a single monolithic chip. Internal recirculation logic plus TTL/DTL level clock signals plus TRI-STATE outputs are provided for maximum interfacing ease.

#### FEATURES

- TRI-STATE MOS OUTPUTS - PROVIDE POWERFUL BUSSING CAPABILITY
- TTL/DTL COMPATIBLE CLOCKS - PROVIDE EXTREMELY LOW CLOCK CAPACITANCE
- RECIRCULATION PATH ON CHIP
- THREE BIT LENGTHS AVAILABLE
- HIGH FREQUENCY OPERATION
- 1.5MHz GUARANTEED CLOCK RATE
- TTL, DTL COMPATIBLE SIGNALS
- STANDARD PACKAGES - 10 LEAD TO-100, 14 PIN DIP
- SIGNETICS P-MOS SILICON GATE PROCESS TECHNOLOGY

#### APPLICATIONS

LOW COST SEQUENTIAL ACCESS MEMORIES  
LOW COST STATIC BUFFER MEMORIES  
CRT REFRESH MEMORIES - LINE STORAGE

#### SPECIAL FEATURES

The three clock phases used by the register cells are generated internally by an on-chip generator. This clock generator is controlled by a single TTL/DTL 5V logic level input.

The output has three states:

"1" low impedance to +5V

"0" low impedance to -5V

"OFF" high impedance  $\approx 10$  M ohm

The "OFF" state is controlled by the Output Enable control input.

#### PROCESS TECHNOLOGY

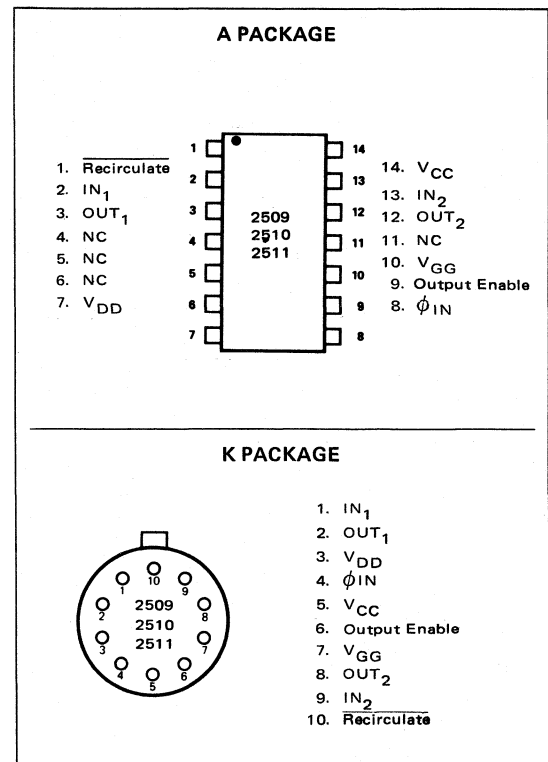
Use of low threshold silicon gate technology allows high speed (1.5MHz Guaranteed) while reducing power dissipation and clock input capacitance dramatically as compared to conventional technologies.

The use of low voltage circuitry minimizes power dissipation and facilitates interfacing with bipolar integrated circuits.

#### BIPOLAR COMPATIBILITY

The clock and signal inputs of these registers can be driven directly by standard bipolar integrated (TTL, DTL, etc.) circuits, by CMOS circuits, or by other MOS circuits. The TRI-STATE output stage provides sufficient current to drive one standard TTL load.

#### PIN CONFIGURATIONS (Top View)



#### PART IDENTIFICATION TABLE

PART NUMBER	BIT LENGTH	PACKAGE
2509K	Dual 50	10 Pin, TO-100
2509A	Dual 50	14 Pin, DIP
2510K	Dual 100	10 Pin, TO-100
2510A	Dual 100	14 Pin, DIP
2511K	Dual 200	10 Pin, TO-100
2511A	Dual 200	14 Pin, DIP

# SIGNETICS TRI-STATE OUTPUT DUAL 50-100-200 BIT STATIC SHIFT REGISTERS ■ 2509/10/11

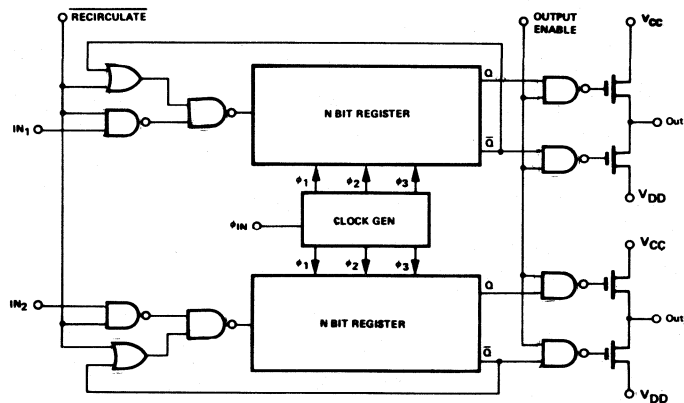
## MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature (2)	0°C to +70°C
Storage Temperature	-65°C to +150°C
Package Power Dissipation (A & K) (Note 2) @ T <sub>A</sub> = 70°C	535mW
Data and Clock Input Voltages and Supply Voltages with respect to V <sub>CC</sub> (3)	+0.3V to -20V

## NOTES:

1. Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W.
3. All inputs are protected against static charge accumulation.
4. Parameters are valid over operating temperature range unless otherwise specified.
5. All voltage measurements are referenced to ground.
6. Manufacturer reserves the right to make design and process changes and improvements.
7. Typical values are at +25°C and nominal supply voltages.
8. Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.

## BLOCK DIAGRAM



### NOTES:

- 1: If output enable = "0", output is "off".
- 2: If output enable = "1", see Truth Table.

### TRUTH TABLE:

RECIRCULATE	INPUT	FUNCTION
0	0	Recirculate
0	1	Recirculate
1	0	"0" is Written
1	1	"1" is Written

NOTE: "0" = 0V; "1" = +5V.

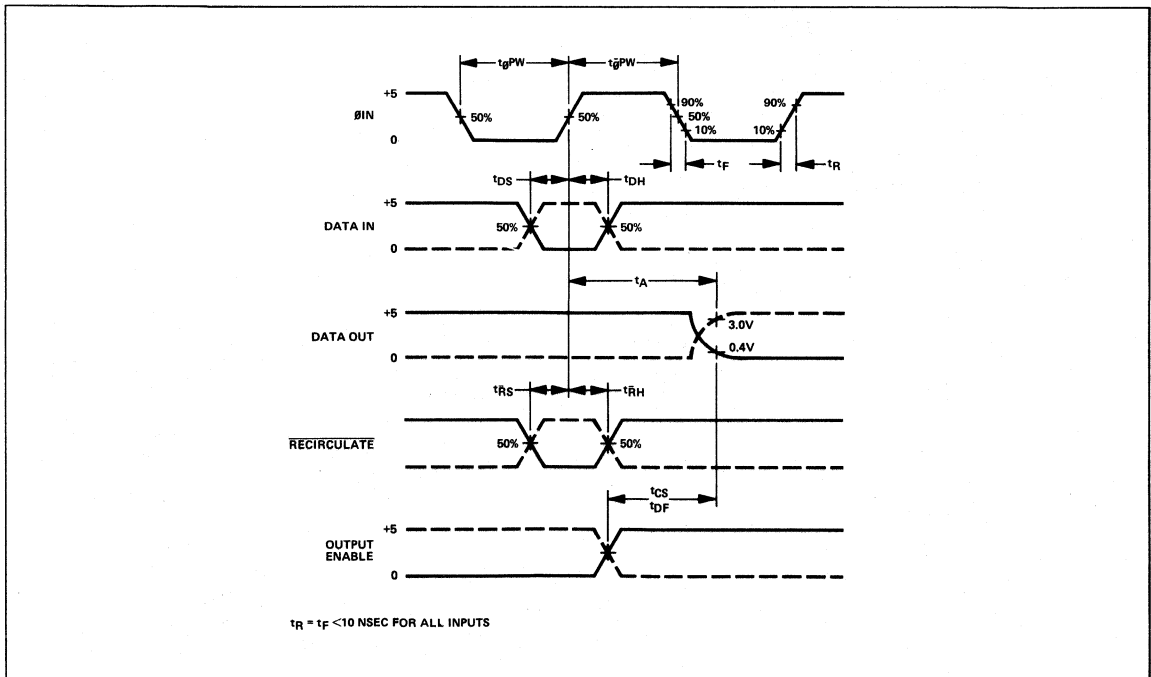
# SIGNETICS TRI-STATE OUTPUT DUAL 50-100-200 BIT STATIC SHIFT REGISTERS ■ 2509/10/11

## DC CHARACTERISTICS

$T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ;  $V_{CC} = +5\text{V}$  (8);  $V_{DD} = -5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$  unless otherwise noted. (Notes 4,5,6,7)

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$I_{LI}$	Input Load Current		10	500	nA	$V_{IN} = -5.5\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{LO}$	Output Leakage Current		10	1000	nA	$V_{CE} = 1.05\text{V}$ , $T_A = 25^\circ\text{C}$ , $V_{OUT} = -5\text{V}$
$I_{LC}$	Clock Leakage Current		10	500	nA	$V_{ILC} = \text{GND}$ , $T_A = 25^\circ\text{C}$
$I_{DD}$	Power Supply Current					
	(Dual 50)		6.5	15	mA	Continuous Operation
	(Dual 100)		12	30	mA	$F = 1.5\text{MHz}$ , $T_A = 25^\circ\text{C}$
(Dual 200)		20	40	mA		
$I_{GG}$	Power Supply Current		4.5	7.5	mA	
$V_{IL}$	Input "Low" Voltage			+0.6	V	Note 8
$V_{IH}$	Input "High" Voltage	+3.4		5.3	V	Note 8
$V_{ILC}$	Clock Input "Low" Voltage	-5		+0.6	V	Note 8
$V_{IHC}$	Clock Input "High" Voltage	+3.4		5.3	V	Note 8

## TIMING DIAGRAM



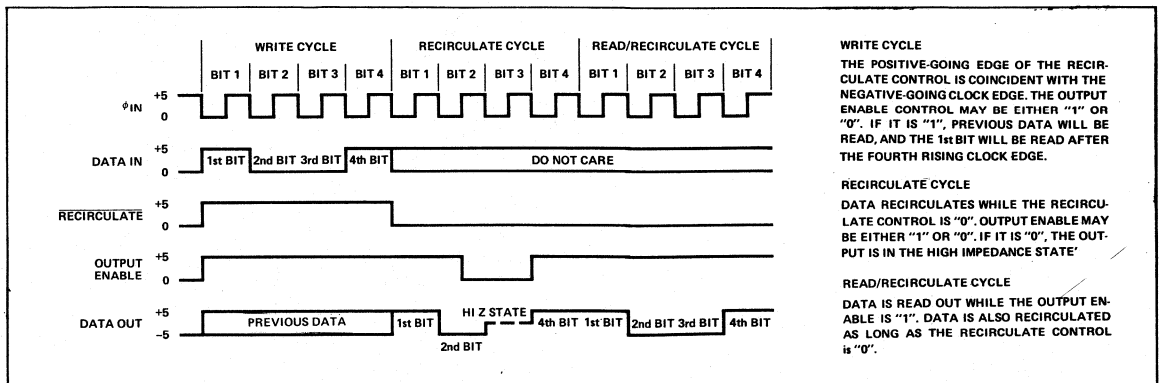
# SIGNETICS TRI-STATE OUTPUT DUAL 50-100-200 BIT STATIC SHIFT REGISTERS ■ 2509/10/11

## AC CHARACTERISTICS

$V_{CC} = +5V (8)$ ;  $V_{DD} = -5V \pm 5\%$ ;  $V_{ILC} = +0.4V$  to  $4V$ ;  $V_{GG} = -12V \pm 5\%$ ;  $T_A = 0^\circ C$  to  $+70^\circ C$

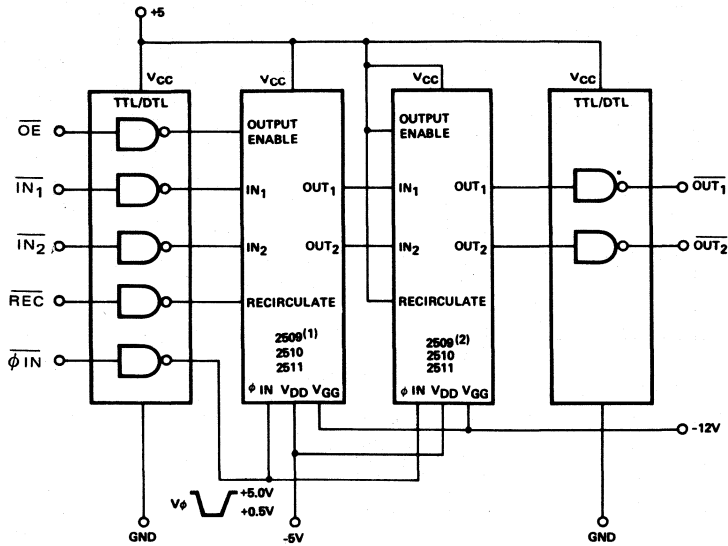
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
Frequency	Clock Rep Rate	DC	3	1.5	MHz	
$t_{\phi PW}$	Clock Pulse Width	.290	.150	100	$\mu sec$	
$\overline{t_{\phi PW}}$	Clock Pulse Width	.210		DC	$\mu sec$	
$t_R, t_F$	Clock Pulse Transition			1	$\mu sec$	
$t_{DS}$	Data Write (Set-up) Time	50			nsec	
$t_{DH}$	Data to Clock Hold Time	50			nsec	
$t_A$	Clock to Data Out Delay		200	350	nsec	
$t_A$	Clock to Data Out Delay			500	nsec	$I_{OL} = 1.6mA$
$t_{CS}$	Output Enable to Data Out			300	nsec	
$t_{DE}$	Output Enable to Data Out Disconnect			300	nsec	
$C_{IN}$	Input Capacitance			5	pF	@ 1 MHz; $V_{IN} = V_{CC}$ ; $V_{AC} = 25mV$ p-p
$C_{OUT}$	Output Capacitance			5	pF	@ 1 MHz; $V_{OUT} = V_{CC}$ ; $V_{AC} = 25mV$ p-p
$C_{\phi}$	Clock Capacitance			5	pF	@ 1 MHz; $V_{\phi} = V_{CC}$ ; $V_{AC} = 25mV$ p-p
$V_{OL}$	Output "Low" Voltage			+0.5	V	$I_{OL} = 1.6mA$
$V_{OHI}$	Output "High" Voltage	+3.8	3.5		V	$I_{OH} = 100\mu A$
	Driving MOS	3.6				

## TIMING EXAMPLE FOR 4-BIT SHIFT REGISTER



APPLICATIONS INFORMATION

TTL/DTL/MOS INTERFACES

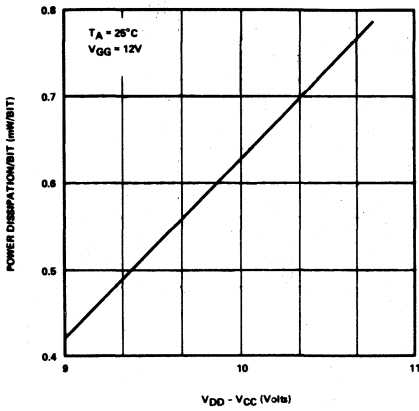


NOTES:

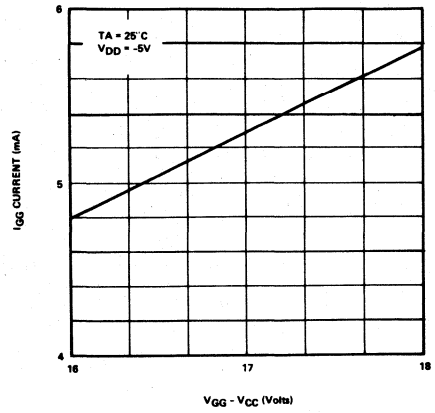
1. Register used as a recirculating register.
2. Register used as serial in/serial out shift register.

TYPICAL CHARACTERISTIC CURVES

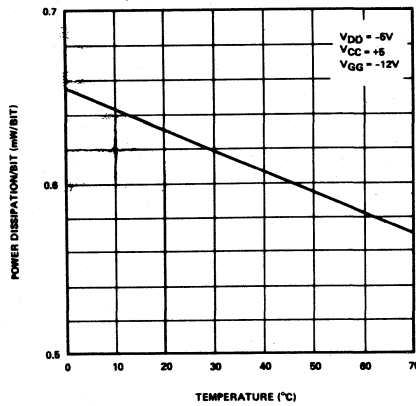
POWER DISSIPATION/BIT VERSUS  $V_{DD}$  SUPPLY VOLTAGE



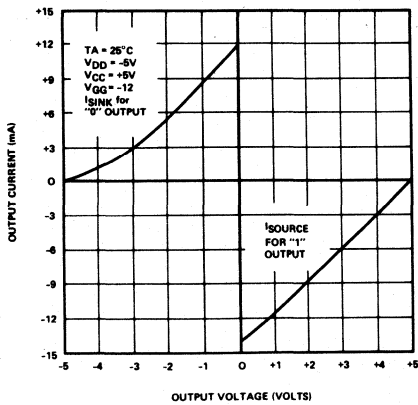
$I_{GG}$  CURRENT VERSUS  $V_{GG}$  SUPPLY VOLTAGE



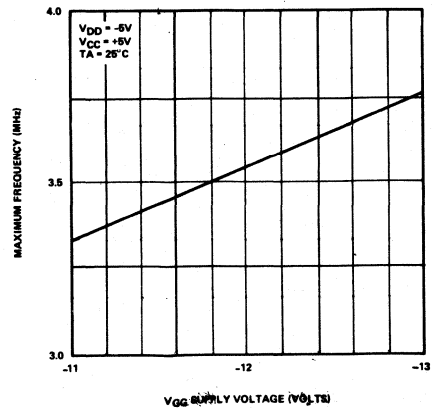
POWER DISSIPATION/BIT VERSUS TEMPERATURE



OUTPUT VOLTAGE VERSUS OUTPUT CURRENT



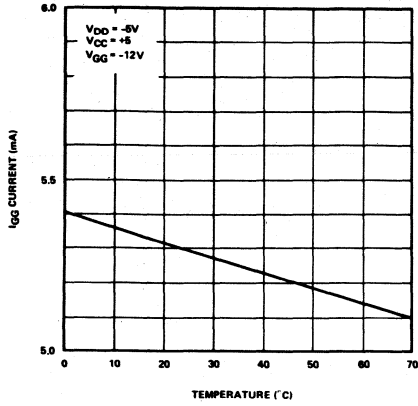
MAXIMUM FREQUENCY VERSUS  $V_{GG}$  SUPPLY VOLTAGE



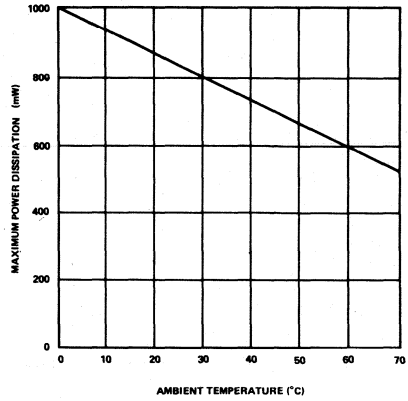


TYPICAL CHARACTERISTIC CURVES (Cont'd.)

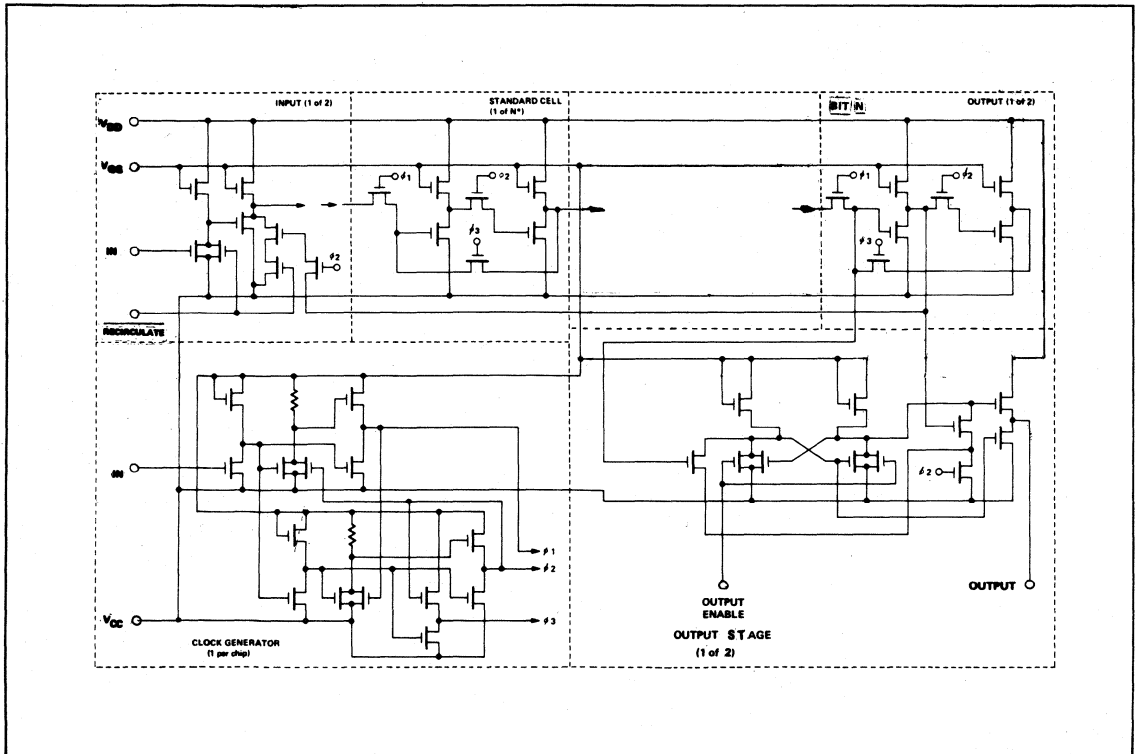
$I_{GG}$  CURRENT  
VERSUS TEMPERATURE



PACKAGE MAXIMUM  
POWER DISSIPATION



SCHEMATIC DIAGRAM



### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

The Signetics 2513 is a high speed 2560-bit Static ROM organized as 64x8x5. A standard 7x5 dot matrix fits well in the 2513. The product uses +5V, -5V and -12V power supplies, TTL level interface signals and Tri-State Outputs for direct, low cost interfacing with TTL, DTL, CMOS and 2500 Series MOS.

#### FEATURES

- 450 ns TYPICAL ACCESS TIME
- STATIC OPERATION
- TTL/DTL COMPATIBLE INPUTS
- +5, -5, -12V POWER SUPPLIES
- TRI-STATE OUTPUT CONTROLLED BY CHIP ENABLE FOR BUSSING CAPABILITY
- 2513/CM2140 ASCII FONT STANDARD (7 X 5)
- 24-PIN DIP
- P-MOS SILICON GATE TECHNOLOGY

#### APPLICATIONS

RASTER SCAN CRT DISPLAYS (ROW OUTPUT)  
 PRINTER CHARACTER GENERATOR  
 PANEL DISPLAYS AND BILLBOARDS  
 MICRO-PROGRAMMING  
 CODE CONVERSION

#### PROCESS TECHNOLOGY

The use of Signetics' P channel Silicon Gate Process allows the design and production of higher functional density and operating speed than other techniques.

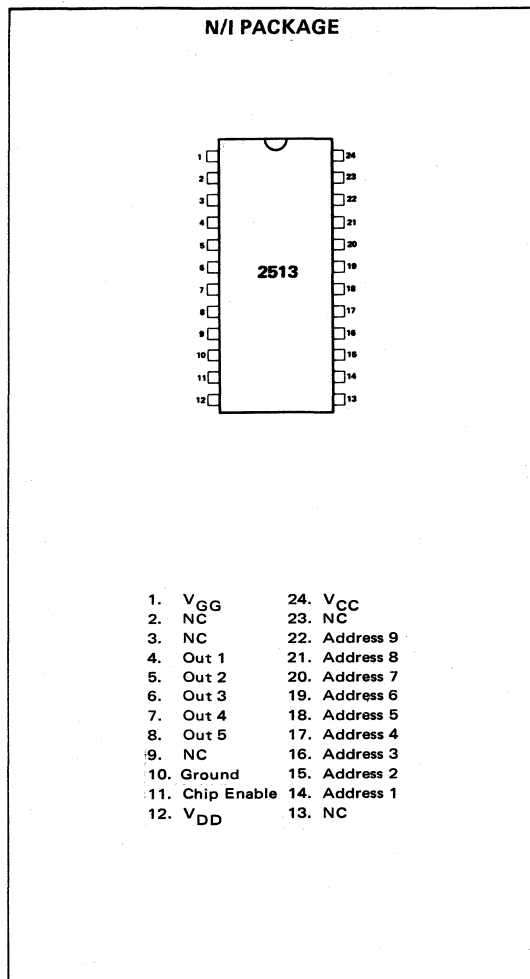
#### SILICONE PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process the silicon material over the gate oxide passivates the MOS transistors. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability, superior moisture resistance, and ionic contamination barriers.

#### BIPOLAR COMPATIBILITY

All inputs of the 2513 can be driven directly by standard TTL voltage levels. The data output buffers are capable of sinking a minimum of 1.6 mA, sufficient to drive one standard TTL load.

#### PIN CONFIGURATION (Top View)



#### PART IDENTIFICATION TABLE

PART	ORGANIZATION	PROGRAMMING
2513N/I CM2140	64X8X5	ASCII Font
2513N/I CMXXXX	64X7X5 64X8X5	Custom

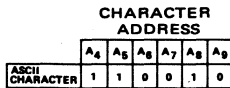
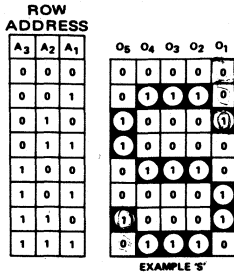
N PACKAGE = 24 PIN SILICONE DIP

I PACKAGE = 24 PIN CERAMIC DIP

CHARACTER FORMAT

MAXIMUM GUARANTEED RATINGS(1)

Operating Ambient Temperature	0°C to 70°C
Storage Temperature	-65°C to +150°C
Package Power Dissipation(2) @T <sub>A</sub> 70°C	730mW
Input(3) and Supply Voltages with respect to V <sub>CC</sub>	+0.3 to -20V



NOTES

1. Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 110°C/W junction to ambient.
3. All inputs are protected against static charge.
4. Parameters are valid over operating temperature range unless specified.
5. All voltage measurements are referenced to ground.
6. Manufacturer reserves the right to make design and process changes and improvements.
7. Typical values are at +25°C and nominal supply voltages.
8. Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.

DC CHARACTERISTICS

T<sub>A</sub> = 0°C to +70°C; V<sub>CC</sub> = +5V ±5%; V<sub>DD</sub> = -5V ±5%; V<sub>GG</sub> = -12V ±5% unless otherwise noted. (Notes 4, 5, 6, 7)

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current		10	500	nA	V <sub>IN</sub> = -5.5V T <sub>A</sub> = 25°C
I <sub>LO</sub>	Output Leakage Current		10	1000	nA	V <sub>OUT</sub> = -5.5V T <sub>A</sub> = 25°C V <sub>CE</sub> = V <sub>CC</sub>
I <sub>DD</sub>	V <sub>DD</sub> Power Supply Current		12	15	mA	Outputs Open
I <sub>GG</sub>	V <sub>GG</sub> Power Supply Current		10	15	mA	Outputs Open V <sub>CE</sub> = V <sub>CC</sub>
V <sub>IL</sub>	Input Logic "0"			+0.6	V	Note 8
V <sub>IH</sub>	Input Logic "1"	+3.4		5.3	V	Note 8

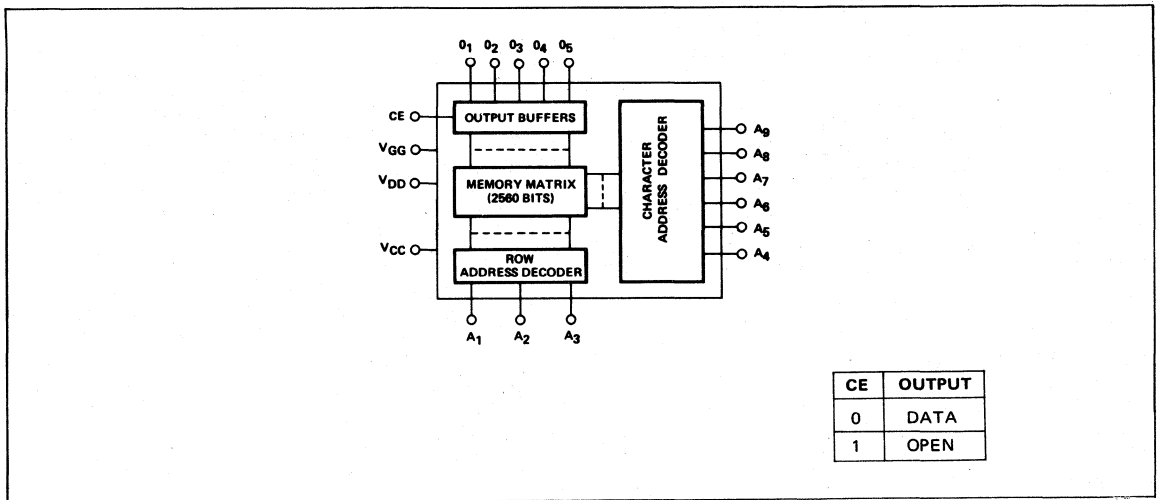
# SIGNETICS 64 X 8 X 5 CHARACTER GENERATOR ■ 2513

## AC CHARACTERISTICS

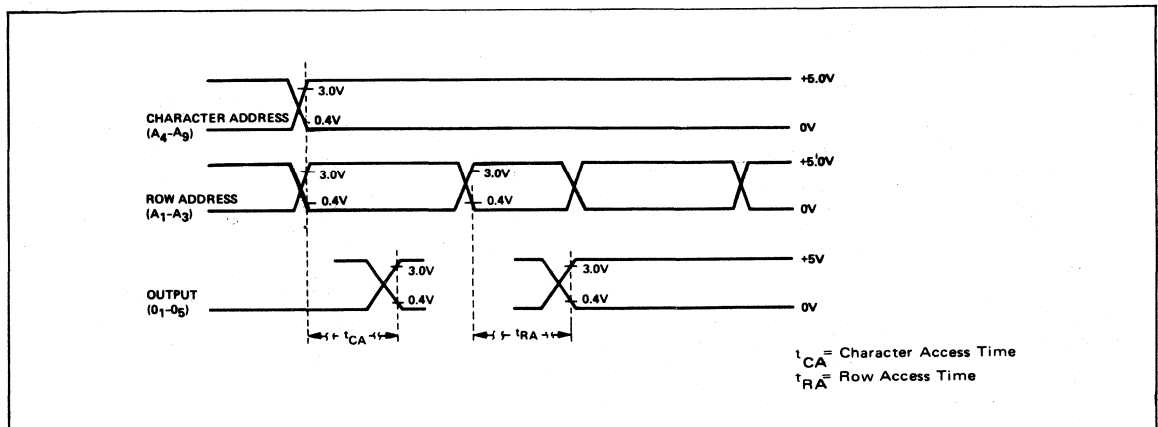
$T_A = 0^{\circ}\text{C}$  to  $+70^{\circ}\text{C}$ ;  $V_{CC} = 5\text{V} \pm 5\%$ ;  $V_{DD} = -5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$ ; unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$V_{OL}$	Output Logic "Zero"	-5		0.4	V	One TTL Load
$V_{OH}$	Output Logic "One"	3.0			V	One TTL Load
$t_{CA}(CM2140)$	Character Access Time		500	600	ns	See AC Test Setup
$t_{RA}$	Row Access Time ( $A_1 - A_3$ )		450	500	ns	See AC Test Setup
$t_{CE}$	Chip Enable to Output		150		ns	
$C_{IN}$	Address Input Capacitance			10	pF	$f = 1\text{ MHz}$ , $V_{IH} = V_{CC}$ , 25mV p-p

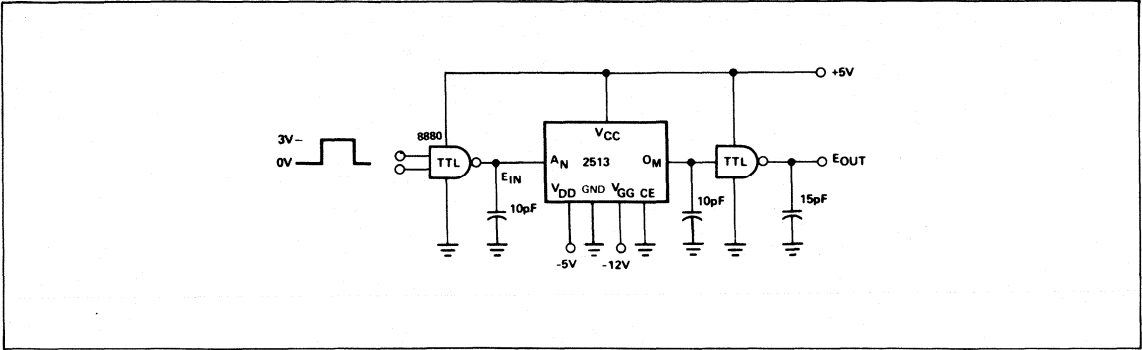
## BLOCK DIAGRAM



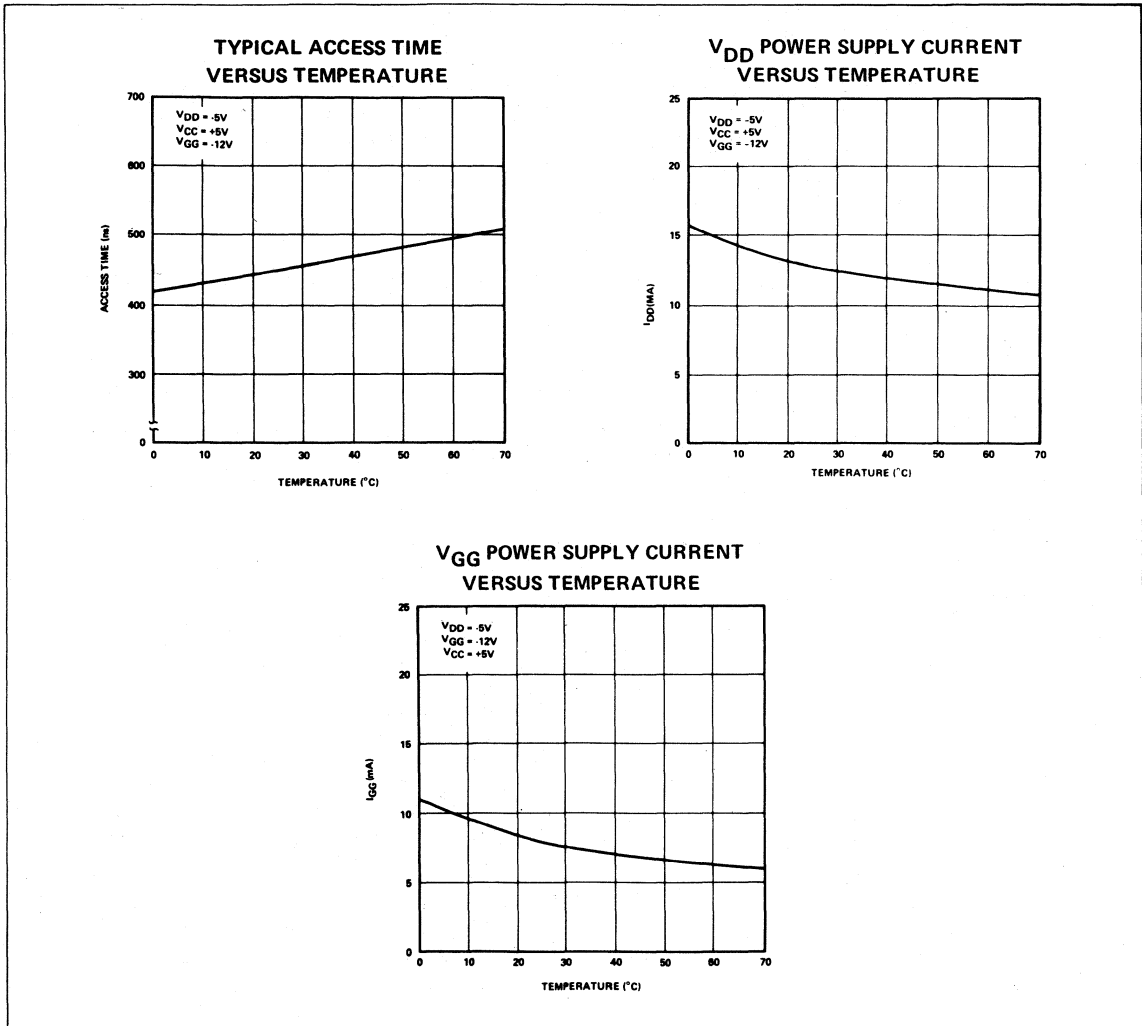
## TIMING DIAGRAM



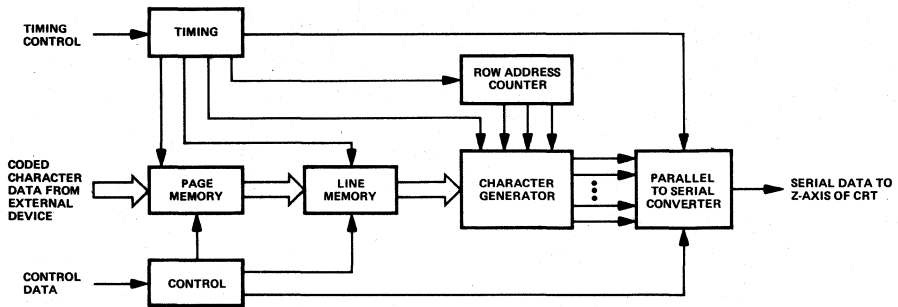
AC TEST SETUP



TYPICAL CHARACTERISTIC CURVES



APPLICATIONS INFORMATION



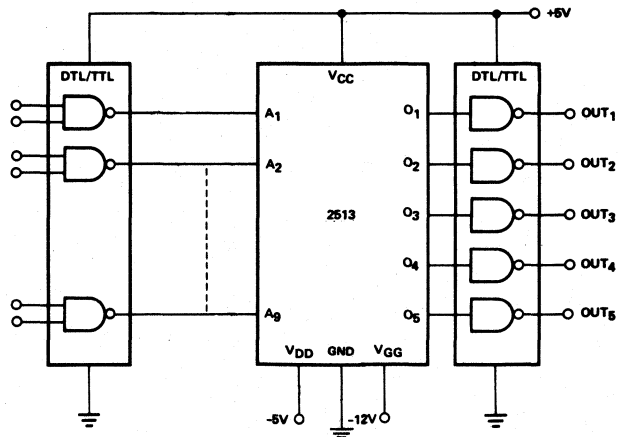
APPLICATION INFORMATION

CHARACTER GENERATOR: The 2513 IS DESIGNED TO PROVIDE THE INFORMATION NEEDED TO CONVERT THE CHARACTER CODES INTO A DOT MATRIX FOR DISPLAY.

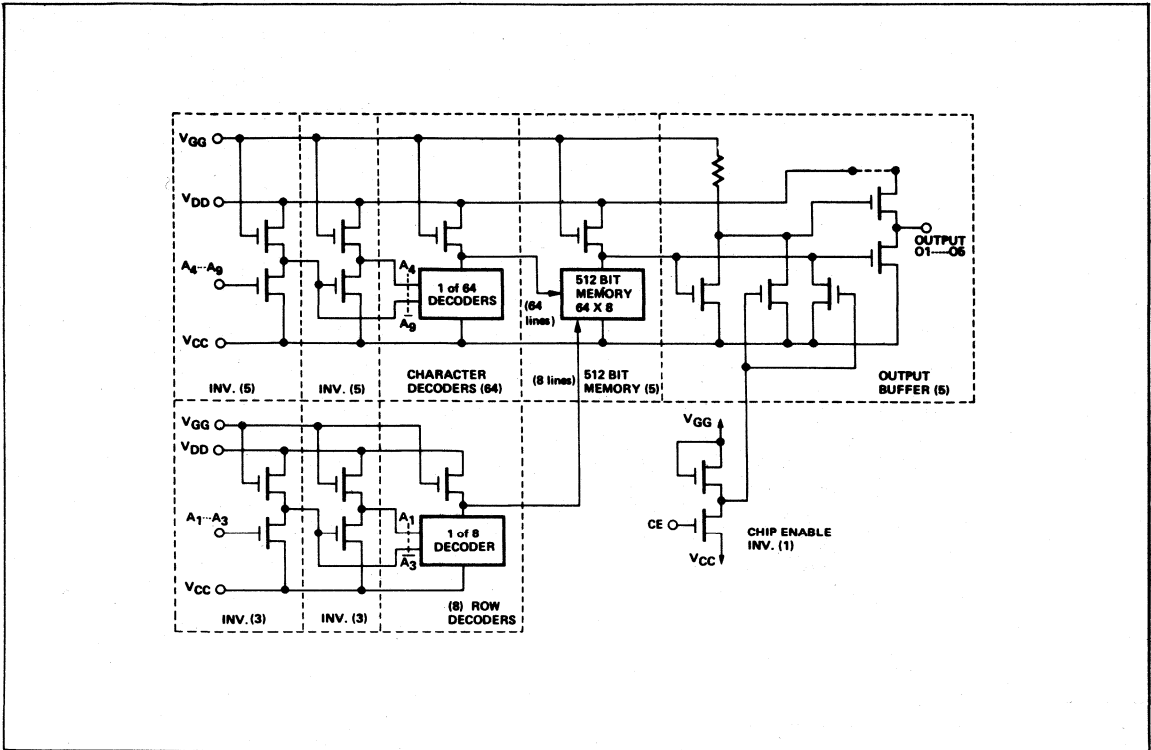
PAGE MEMORY: THIS MEMORY CONTAINS CHARACTER CODES. TYPICALLY, IT CONTAINS THE SAME NUMBER OF CHARACTER CODES AS THE NUMBER OF CHARACTERS ON A FULL SCREEN.

LINE MEMORY: THIS MEMORY CONTAINS THE CHARACTER CODES FOR ONE LINE OF THE CRT DISPLAY.

DTL/TTL INTERFACING

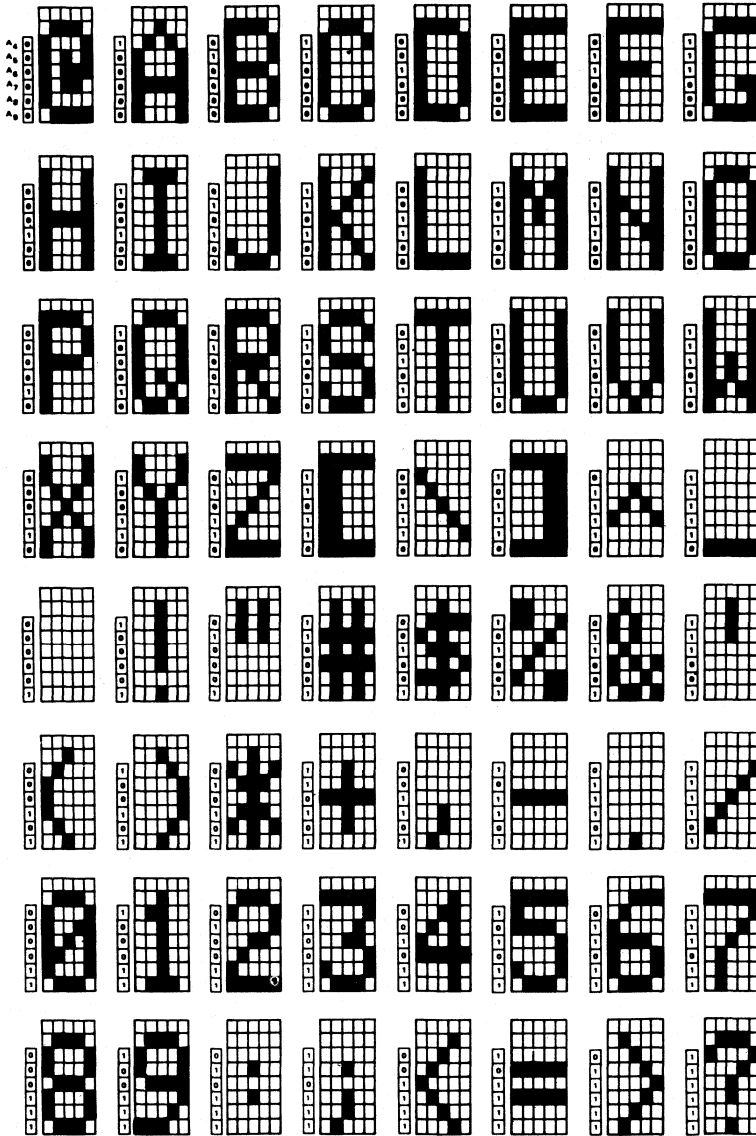


CIRCUIT CROSS-SECTION



ASCII CHARACTER FONT

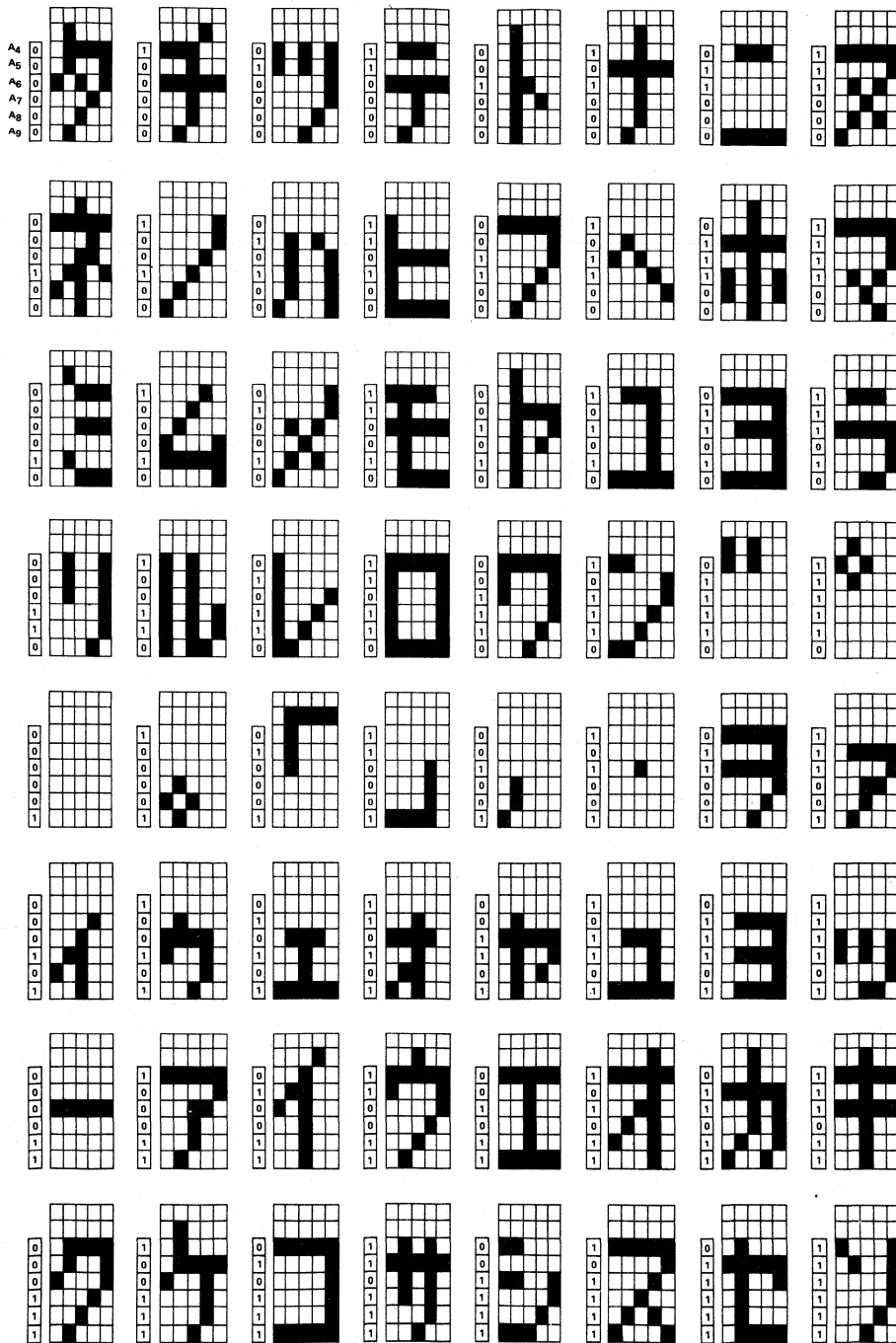
2513N/CM2140





JAPANESE KATAKANA FONT

2513N/CM4800



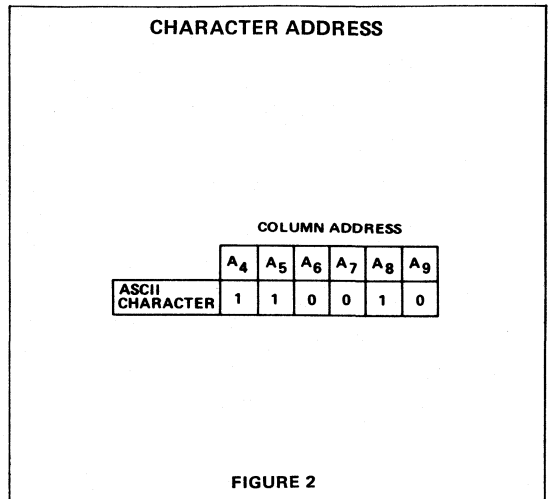
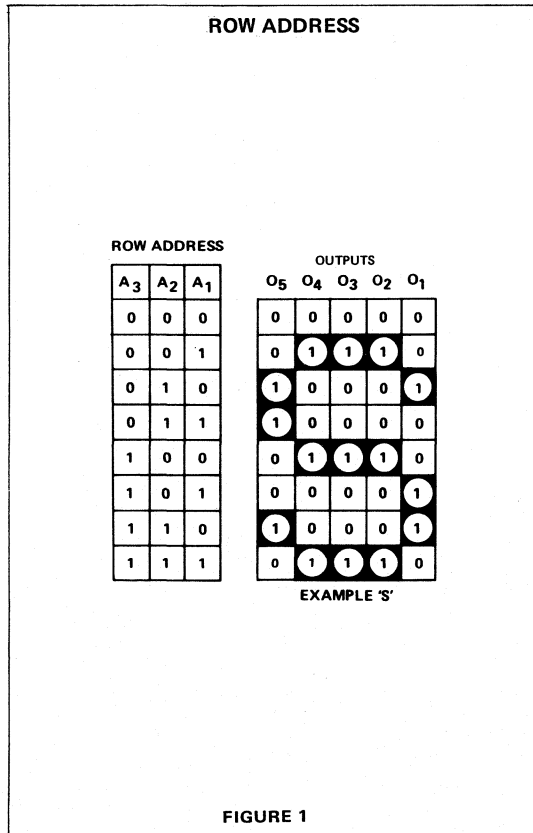
# SIGNETICS 64 X 8 X 5 CHARACTER GENERATOR ■ 2513

COMPANY \_\_\_\_\_  
 ADDRESS \_\_\_\_\_  
 CITY \_\_\_\_\_ STATE \_\_\_\_\_ ZIP \_\_\_\_\_  
 TELEPHONE \_\_\_\_\_  
 AUTHORIZED SIGNATURE \_\_\_\_\_  
 DATE \_\_\_\_\_  
 CUSTOMER PRINT OR ID NO. \_\_\_\_\_  
 PURCHASE ORDER NUMBER \_\_\_\_\_  
 DEVICE TYPE \_\_\_\_\_ 2513 \_\_\_\_\_  
 CUSTOM PATTERN NUMBER (TO BE ENTERED BY  
 SIGNETICS) \_\_\_\_\_

## ORGANIZATION AS CHARACTER GENERATOR

A six-bit binary address ( $A_4$  through  $A_9$ ) selects 1-of-64 matrix characters arranged 5 dots horizontally and 8 dots vertically. A three bit binary address code ( $A_1$  through  $A_3$ ) selects 1 of 8 rows. Five outputs display a complete row of the character matrix. See Figure 1. The devices may also be used in pairs to provide 9 X 7 and 10 X 8 vertical scan formats.

## CHARACTER FORMAT



## ORGANIZATION AS READ-ONLY MEMORY

For a straight 512 X 5 read-only memory, the five outputs will display any one of 512 5-bit stored words corresponding to a 9-bit address applied to  $A_1$  through  $A_9$ .

## CUSTOM DEVICES

For unique custom memory patterns, this form should be used to transmit coding instructions. The nomenclature for a custom device will consist of the basic product type followed by a unique CM number assigned by Signetics. For example, "2513N/CM2141".

- **PROGRAMMING WITH PUNCHED CARDS**  
 For maximum accuracy and minimum cost and turn-around time, the truth table should be transmitted to Signetics in the form of punched cards according to the format indicated on the following pages.
- **PROGRAMMING WITH WRITTEN TRUTH TABLE**  
 When punched data cards cannot be supplied, the truth table may be transmitted in written form using the attached blank truth table.

## VERIFICATION

Upon receipt of either punched card or written truth table information, Signetics will prepare a computer tabulation of the instructions and return to the address indicated. If errors are detected, they should be transmitted to Signetics as quickly as possible.

## LOGIC CONVENTION

Logic "1"s or blackened squares in the truth table will result in "high" output from the indicated output terminal (i.e. 3.2V minimum). Similarly, a "1" address input level is interpreted as 3.2V minimum.



SIGNETICS 64 X 8 X 5 CHARACTER GENERATOR ■ 2513

DATA CARDS

OUTPUTS 0<sub>5</sub> THROUGH 0<sub>1</sub> RESPECTIVELY

CHARACTER NUMBER  
(DATA CARD NUMBER)

00000	01110	10001	00001	00010	00100	00000	00100	063
00000	01110	10001	00001	00010	00100	00000	00100	063

ROW ADDRESS

000	001	010	011	100	101	110	111	
00000	01110	10001	10111	10101	10111	10000	01110	008
00000	01110	10001	10111	10101	10111	10000	01110	008

BASIC DEVICE TYPE

LEAVE COLS. 10, 11, 12, 13 BLANK FOR ASSIGNMENT OF CM NO. BY SIGNETICS

2513NX/CM							
00000	01110	10001	10111	10101	10111	10000	01110

NOTE: "Character" number is in columns 78, 79, and 80. Note that each group of eight 5-bit words is treated as a character for convenience of coding.

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
0 0 0 0 0 0 0 0 0	000						
0 0 0 0 0 0 0 0 1	001						
0 0 0 0 0 0 0 1 0	002						
0 0 0 0 0 0 0 1 1	003						
0 0 0 0 0 0 1 0 0	004						
0 0 0 0 0 0 1 0 1	005						
0 0 0 0 0 0 1 1 0	006						
0 0 0 0 0 0 1 1 1	007						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
0 0 0 1 0 0 0 0 0	032						
0 0 0 1 0 0 0 0 1	033						
0 0 0 1 0 0 0 1 0	034						
0 0 0 1 0 0 0 1 1	035						
0 0 0 1 0 0 1 0 0	036						
0 0 0 1 0 0 1 0 1	037						
0 0 0 1 0 0 1 1 0	038						
0 0 0 1 0 0 1 1 1	039						

0 0 0 0 0 1 0 0 0	008						
0 0 0 0 0 1 0 0 1	009						
0 0 0 0 0 1 0 1 0	010						
0 0 0 0 0 1 0 1 1	011						
0 0 0 0 0 1 1 0 0	012						
0 0 0 0 0 1 1 0 1	013						
0 0 0 0 0 1 1 1 0	014						
0 0 0 0 0 1 1 1 1	015						

0 0 0 1 0 1 0 0 0	040						
0 0 0 1 0 1 0 0 1	041						
0 0 0 1 0 1 0 1 0	042						
0 0 0 1 0 1 0 1 1	043						
0 0 0 1 0 1 1 0 0	044						
0 0 0 1 0 1 1 0 1	045						
0 0 0 1 0 1 1 1 0	046						
0 0 0 1 0 1 1 1 1	047						

0 0 0 0 1 0 0 0 0	016						
0 0 0 0 1 0 0 0 1	017						
0 0 0 0 1 0 0 1 0	018						
0 0 0 0 1 0 0 1 1	019						
0 0 0 0 1 0 1 0 0	020						
0 0 0 0 1 0 1 0 1	021						
0 0 0 0 1 0 1 1 0	022						
0 0 0 0 1 0 1 1 1	023						

0 0 0 1 1 0 0 0 0	048						
0 0 0 1 1 0 0 0 1	049						
0 0 0 1 1 0 0 1 0	050						
0 0 0 1 1 0 0 1 1	051						
0 0 0 1 1 0 1 0 0	052						
0 0 0 1 1 0 1 0 1	053						
0 0 0 1 1 0 1 1 0	054						
0 0 0 1 1 0 1 1 1	055						

0 0 0 0 1 1 0 0 0	024						
0 0 0 0 1 1 0 0 1	025						
0 0 0 0 1 1 0 1 0	026						
0 0 0 0 1 1 0 1 1	027						
0 0 0 0 1 1 1 0 0	028						
0 0 0 0 1 1 1 0 1	029						
0 0 0 0 1 1 1 1 0	030						
0 0 0 0 1 1 1 1 1	031						

0 0 0 1 1 1 0 0 0	056						
0 0 0 1 1 1 0 0 1	057						
0 0 0 1 1 1 0 1 0	058						
0 0 0 1 1 1 0 1 1	059						
0 0 0 1 1 1 1 0 0	060						
0 0 0 1 1 1 1 0 1	061						
0 0 0 1 1 1 1 1 0	062						
0 0 0 1 1 1 1 1 1	063						

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ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
0 0 1 0 0 0 0 0 0	064						
0 0 1 0 0 0 0 0 1	065						
0 0 1 0 0 0 0 1 0	066						
0 0 1 0 0 0 0 1 1	067						
0 0 1 0 0 0 1 0 0	068						
0 0 1 0 0 0 1 0 1	069						
0 0 1 0 0 0 1 1 0	070						
0 0 1 0 0 0 1 1 1	071						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
0 0 1 1 0 0 0 0 0	096						
0 0 1 1 0 0 0 0 1	097						
0 0 1 1 0 0 0 1 0	098						
0 0 1 1 0 0 0 1 1	099						
0 0 1 1 0 0 1 0 0	100						
0 0 1 1 0 0 1 0 1	101						
0 0 1 1 0 0 1 1 0	102						
0 0 1 1 0 0 1 1 1	103						

0 0 1 0 0 1 0 0 0	072						
0 0 1 0 0 1 0 0 1	073						
0 0 1 0 0 1 0 1 0	074						
0 0 1 0 0 1 0 1 1	075						
0 0 1 0 0 1 1 0 0	076						
0 0 1 0 0 1 1 0 1	077						
0 0 1 0 0 1 1 1 0	078						
0 0 1 0 0 1 1 1 1	079						

0 0 1 1 0 1 0 0 0	104						
0 0 1 1 0 1 0 0 1	105						
0 0 1 1 0 1 0 1 0	106						
0 0 1 1 0 1 0 1 1	107						
0 0 1 1 0 1 1 0 0	108						
0 0 1 1 0 1 1 0 1	109						
0 0 1 1 0 1 1 1 0	110						
0 0 1 1 0 1 1 1 1	111						

0 0 1 0 1 0 0 0 0	080						
0 0 1 0 1 0 0 0 1	081						
0 0 1 0 1 0 0 1 0	082						
0 0 1 0 1 0 0 1 1	083						
0 0 1 0 1 0 1 0 0	084						
0 0 1 0 1 0 1 0 1	085						
0 0 1 0 1 0 1 1 0	086						
0 0 1 0 1 0 1 1 1	087						

0 0 1 1 1 0 0 0 0	112						
0 0 1 1 1 0 0 0 1	113						
0 0 1 1 1 0 0 1 0	114						
0 0 1 1 1 0 0 1 1	115						
0 0 1 1 1 0 1 0 0	116						
0 0 1 1 1 0 1 0 1	117						
0 0 1 1 1 0 1 1 0	118						
0 0 1 1 1 0 1 1 1	119						

0 0 1 0 1 1 0 0 0	088						
0 0 1 0 1 1 0 0 1	089						
0 0 1 0 1 1 0 1 0	090						
0 0 1 0 1 1 0 1 1	091						
0 0 1 0 1 1 1 0 0	092						
0 0 1 0 1 1 1 0 1	093						
0 0 1 0 1 1 1 1 0	094						
0 0 1 0 1 1 1 1 1	095						

0 0 1 1 1 1 0 0 0	120						
0 0 1 1 1 1 0 0 1	121						
0 0 1 1 1 1 0 1 0	122						
0 0 1 1 1 1 0 1 1	123						
0 0 1 1 1 1 1 0 0	124						
0 0 1 1 1 1 1 0 1	125						
0 0 1 1 1 1 1 1 0	126						
0 0 1 1 1 1 1 1 1	127						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
0 1 0 0 0 0 0 0 0	128						
0 1 0 0 0 0 0 0 1	129						
0 1 0 0 0 0 0 1 0	130						
0 1 0 0 0 0 0 1 1	131						
0 1 0 0 0 0 1 0 0	132						
0 1 0 0 0 0 1 0 1	133						
0 1 0 0 0 0 1 1 0	134						
0 1 0 0 0 0 1 1 1	135						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
0 1 0 1 0 0 0 0 0	160						
0 1 0 1 0 0 0 0 1	161						
0 1 0 1 0 0 0 1 0	162						
0 1 0 1 0 0 0 1 1	163						
0 1 0 1 0 0 1 0 0	164						
0 1 0 1 0 0 1 0 1	165						
0 1 0 1 0 0 1 1 0	166						
0 1 0 1 0 0 1 1 1	167						

0 1 0 0 0 1 0 0 0	136						
0 1 0 0 0 1 0 0 1	137						
0 1 0 0 0 1 0 1 0	138						
0 1 0 0 0 1 0 1 1	139						
0 1 0 0 0 1 1 0 0	140						
0 1 0 0 0 1 1 0 1	141						
0 1 0 0 0 1 1 1 0	142						
0 1 0 0 0 1 1 1 1	143						

0 1 0 1 0 1 0 0 0	168						
0 1 0 1 0 1 0 0 1	169						
0 1 0 1 0 1 0 1 0	170						
0 1 0 1 0 1 0 1 1	171						
0 1 0 1 0 1 1 0 0	172						
0 1 0 1 0 1 1 0 1	173						
0 1 0 1 0 1 1 1 0	174						
0 1 0 1 0 1 1 1 1	175						

0 1 0 0 1 0 0 0 0	144						
0 1 0 0 1 0 0 0 1	145						
0 1 0 0 1 0 0 1 0	146						
0 1 0 0 1 0 0 1 1	147						
0 1 0 0 1 0 1 0 0	148						
0 1 0 0 1 0 1 0 1	149						
0 1 0 0 1 0 1 1 0	150						
0 1 0 0 1 0 1 1 1	151						

0 1 0 1 1 0 0 0 0	176						
0 1 0 1 1 0 0 0 1	177						
0 1 0 1 1 0 0 1 0	178						
0 1 0 1 1 0 0 1 1	179						
0 1 0 1 1 0 1 0 0	180						
0 1 0 1 1 0 1 0 1	181						
0 1 0 1 1 0 1 1 0	182						
0 1 0 1 1 0 1 1 1	183						

0 1 0 0 1 1 0 0 0	152						
0 1 0 0 1 1 0 0 1	153						
0 1 0 0 1 1 0 1 0	154						
0 1 0 0 1 1 0 1 1	155						
0 1 0 0 1 1 1 0 0	156						
0 1 0 0 1 1 1 0 1	157						
0 1 0 0 1 1 1 1 0	158						
0 1 0 0 1 1 1 1 1	159						

0 1 0 1 1 1 0 0 0	184						
0 1 0 1 1 1 0 0 1	185						
0 1 0 1 1 1 0 1 0	186						
0 1 0 1 1 1 0 1 1	187						
0 1 0 1 1 1 1 0 0	188						
0 1 0 1 1 1 1 0 1	189						
0 1 0 1 1 1 1 1 0	190						
0 1 0 1 1 1 1 1 1	191						

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ADDRESS							DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.	
A6	A5	A7	A6-A5	A4	A3	A2		A1	05	04	03	02		01
0	1	1	0	0	0	0	0	192						
0	1	1	0	0	0	0	1	193						
0	1	1	0	0	0	1	0	194						
0	1	1	0	0	0	1	1	195						
0	1	1	0	0	1	0	0	196						
0	1	1	0	0	1	0	1	197						
0	1	1	0	0	1	1	0	198						
0	1	1	0	0	1	1	1	199						

ADDRESS							DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.	
A9	A8	A7	A6	A5	A4	A3		A2	A1	05	04	03		02
0	1	1	1	0	0	0	0	0	224					
0	1	1	1	0	0	0	1	1	225					
0	1	1	1	0	0	1	0	0	226					
0	1	1	1	0	0	1	1	1	227					
0	1	1	1	0	1	0	0	0	228					
0	1	1	1	0	1	0	1	1	229					
0	1	1	1	0	1	1	0	0	230					
0	1	1	1	0	1	1	1	1	231					

0	1	1	0	0	1	0	0	0	200					
0	1	1	0	0	1	0	0	1	201					
0	1	1	0	0	1	0	1	0	202					
0	1	1	0	0	1	0	1	1	203					
0	1	1	0	0	1	1	0	0	204					
0	1	1	0	0	1	1	0	1	205					
0	1	1	0	0	1	1	1	0	206					
0	1	1	0	0	1	1	1	1	207					

0	1	1	1	0	1	0	0	0	232					
0	1	1	1	0	1	0	0	1	233					
0	1	1	1	0	1	0	1	0	234					
0	1	1	1	0	1	0	1	1	235					
0	1	1	1	0	1	1	0	0	236					
0	1	1	1	0	1	1	0	1	237					
0	1	1	1	0	1	1	1	0	238					
0	1	1	1	0	1	1	1	1	239					

0	1	1	0	1	0	0	0	0	208					
0	1	1	0	1	0	0	0	1	209					
0	1	1	0	1	0	0	1	0	210					
0	1	1	0	1	0	0	1	1	211					
0	1	1	0	1	0	1	0	0	212					
0	1	1	0	1	0	1	0	1	213					
0	1	1	0	1	0	1	1	0	214					
0	1	1	0	1	0	1	1	1	215					

0	1	1	1	1	0	0	0	0	240					
0	1	1	1	1	0	0	0	1	241					
0	1	1	1	1	0	0	1	0	242					
0	1	1	1	1	0	0	1	1	243					
0	1	1	1	1	0	1	0	0	244					
0	1	1	1	1	0	1	0	1	245					
0	1	1	1	1	0	1	1	0	246					
0	1	1	1	1	0	1	1	1	247					

0	1	1	0	1	1	0	0	0	216					
0	1	1	0	1	1	0	0	1	217					
0	1	1	0	1	1	0	1	0	218					
0	1	1	0	1	1	0	1	1	219					
0	1	1	0	1	1	1	0	0	220					
0	1	1	0	1	1	1	0	1	221					
0	1	1	0	1	1	1	1	0	222					
0	1	1	0	1	1	1	1	1	223					

0	1	1	1	1	1	0	0	0	248					
0	1	1	1	1	1	0	0	1	249					
0	1	1	1	1	1	0	1	0	250					
0	1	1	1	1	1	0	1	1	251					
0	1	1	1	1	1	1	0	0	252					
0	1	1	1	1	1	1	0	1	253					
0	1	1	1	1	1	1	1	0	254					
0	1	1	1	1	1	1	1	1	255					



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ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
1 0 0 0 0 0 0 0 0	256						
1 0 0 0 0 0 0 0 1	257						
1 0 0 0 0 0 0 1 0	258						
1 0 0 0 0 0 0 1 1	259						
1 0 0 0 0 0 1 0 0	260						
1 0 0 0 0 0 1 0 1	261						
1 0 0 0 0 0 1 1 0	262						
1 0 0 0 0 0 1 1 1	263						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
1 0 0 1 0 0 0 0 0	288						
1 0 0 1 0 0 0 0 1	289						
1 0 0 1 0 0 0 1 0	290						
1 0 0 1 0 0 0 1 1	291						
1 0 0 1 0 0 1 0 0	292						
1 0 0 1 0 0 1 0 1	293						
1 0 0 1 0 0 1 1 0	294						
1 0 0 1 0 0 1 1 1	295						

1 0 0 0 0 1 0 0 0	264						
1 0 0 0 0 1 0 0 1	265						
1 0 0 0 0 1 0 1 0	266						
1 0 0 0 0 1 0 1 1	267						
1 0 0 0 0 1 1 0 0	268						
1 0 0 0 0 1 1 0 1	269						
1 0 0 0 0 1 1 1 0	270						
1 0 0 0 0 1 1 1 1	271						

1 0 0 1 0 1 0 0 0	296						
1 0 0 1 0 1 0 0 1	297						
1 0 0 1 0 1 0 1 0	298						
1 0 0 1 0 1 0 1 1	299						
1 0 0 1 0 1 1 0 0	300						
1 0 0 1 0 1 1 0 1	301						
1 0 0 1 0 1 1 1 0	302						
1 0 0 1 0 1 1 1 1	303						

1 0 0 0 1 0 0 0 0	272						
1 0 0 0 1 0 0 0 1	273						
1 0 0 0 1 0 0 1 0	274						
1 0 0 0 1 0 0 1 1	275						
1 0 0 0 1 0 1 0 0	276						
1 0 0 0 1 0 1 0 1	277						
1 0 0 0 1 0 1 1 0	278						
1 0 0 0 1 0 1 1 1	279						

1 0 0 1 1 0 0 0 0	304						
1 0 0 1 1 0 0 0 1	305						
1 0 0 1 1 0 0 1 0	306						
1 0 0 1 1 0 0 1 1	307						
1 0 0 1 1 0 1 0 0	308						
1 0 0 1 1 0 1 0 1	309						
1 0 0 1 1 0 1 1 0	310						
1 0 0 1 1 0 1 1 1	311						

1 0 0 0 1 1 0 0 0	280						
1 0 0 0 1 1 0 0 1	281						
1 0 0 0 1 1 0 1 0	282						
1 0 0 0 1 1 0 1 1	283						
1 0 0 0 1 1 1 0 0	284						
1 0 0 0 1 1 1 0 1	285						
1 0 0 0 1 1 1 1 0	286						
1 0 0 0 1 1 1 1 1	287						

1 0 0 1 1 1 0 0 0	312						
1 0 0 1 1 1 0 0 1	313						
1 0 0 1 1 1 0 1 0	314						
1 0 0 1 1 1 0 1 1	315						
1 0 0 1 1 1 1 0 0	316						
1 0 0 1 1 1 1 0 1	317						
1 0 0 1 1 1 1 1 0	318						
1 0 0 1 1 1 1 1 1	319						

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ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
1 0 1 0 0 0 0 0 0	320						
1 0 1 0 0 0 0 0 1	321						
1 0 1 0 0 0 0 1 0	322						
1 0 1 0 0 0 0 1 1	323						
1 0 1 0 0 0 1 0 0	324						
1 0 1 0 0 0 1 0 1	325						
1 0 1 0 0 0 1 1 0	326						
1 0 1 0 0 0 1 1 1	327						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
1 0 1 1 0 0 0 0 0	352						
1 0 1 1 0 0 0 0 1	353						
1 0 1 1 0 0 0 1 0	354						
1 0 1 1 0 0 0 1 1	355						
1 0 1 1 0 0 1 0 0	356						
1 0 1 1 0 0 1 0 1	357						
1 0 1 1 0 0 1 1 0	358						
1 0 1 1 0 0 1 1 1	359						

1 0 1 0 0 1 0 0 0	328						
1 0 1 0 0 1 0 0 1	329						
1 0 1 0 0 1 0 1 0	330						
1 0 1 0 0 1 0 1 1	331						
1 0 1 0 0 1 1 0 0	332						
1 0 1 0 0 1 1 0 1	333						
1 0 1 0 0 1 1 1 0	334						
1 0 1 0 0 1 1 1 1	335						

1 0 1 1 0 1 0 0 0	360						
1 0 1 1 0 1 0 0 1	361						
1 0 1 1 0 1 0 1 0	362						
1 0 1 1 0 1 0 1 1	363						
1 0 1 1 0 1 1 0 0	364						
1 0 1 1 0 1 1 0 1	365						
1 0 1 1 0 1 1 1 0	366						
1 0 1 1 0 1 1 1 1	367						

1 0 1 0 1 0 0 0 0	336						
1 0 1 0 1 0 0 0 1	337						
1 0 1 0 1 0 0 1 0	338						
1 0 1 0 1 0 0 1 1	339						
1 0 1 0 1 0 1 0 0	340						
1 0 1 0 1 0 1 0 1	341						
1 0 1 0 1 0 1 1 0	342						
1 0 1 0 1 0 1 1 1	343						

1 0 1 1 1 0 0 0 0	368						
1 0 1 1 1 0 0 0 1	369						
1 0 1 1 1 0 0 1 0	370						
1 0 1 1 1 0 0 1 1	371						
1 0 1 1 1 0 1 0 0	372						
1 0 1 1 1 0 1 0 1	373						
1 0 1 1 1 0 1 1 0	374						
1 0 1 1 1 0 1 1 1	375						

1 0 1 0 1 1 0 0 0	344						
1 0 1 0 1 1 0 0 1	345						
1 0 1 0 1 1 0 1 0	346						
1 0 1 0 1 1 0 1 1	347						
1 0 1 0 1 1 1 0 0	348						
1 0 1 0 1 1 1 0 1	349						
1 0 1 0 1 1 1 1 0	350						
1 0 1 0 1 1 1 1 1	351						

1 0 1 1 1 1 0 0 0	376						
1 0 1 1 1 1 0 0 1	377						
1 0 1 1 1 1 0 1 0	378						
1 0 1 1 1 1 0 1 1	379						
1 0 1 1 1 1 1 0 0	380						
1 0 1 1 1 1 1 0 1	381						
1 0 1 1 1 1 1 1 0	382						
1 0 1 1 1 1 1 1 1	383						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					
		05	04	03	02	01	
1 1 0 0 0 0 0 0 0	384						
1 1 0 0 0 0 0 0 1	385						
1 1 0 0 0 0 0 1 0	386						
1 1 0 0 0 0 0 1 1	387						
1 1 0 0 0 0 1 0 0	388						
1 1 0 0 0 0 1 0 1	389						
1 1 0 0 0 0 1 1 0	390						
1 1 0 0 0 0 1 1 1	391						

ADDRESS A9 A8 A7 A6 A5 A4 A3 A2 A1	DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
		05	04	03	02	01	
1 1 0 1 0 0 0 0 0	416						
1 1 0 1 0 0 0 0 1	417						
1 1 0 1 0 0 0 1 0	418						
1 1 0 1 0 0 0 1 1	419						
1 1 0 1 0 0 1 0 0	420						
1 1 0 1 0 0 1 0 1	421						
1 1 0 1 0 0 1 1 0	422						
1 1 0 1 0 0 1 1 1	423						

1 1 0 0 0 1 0 0 0	392						
1 1 0 0 0 1 0 0 1	393						
1 1 0 0 0 1 0 1 0	394						
1 1 0 0 0 1 0 1 1	395						
1 1 0 0 0 1 1 0 0	396						
1 1 0 0 0 1 1 0 1	397						
1 1 0 0 0 1 1 1 0	398						
1 1 0 0 0 1 1 1 1	399						

1 1 0 1 0 1 0 0 0	424						
1 1 0 1 0 1 0 0 1	425						
1 1 0 1 0 1 0 1 0	426						
1 1 0 1 0 1 0 1 1	427						
1 1 0 1 0 1 1 0 0	428						
1 1 0 1 0 1 1 0 1	429						
1 1 0 1 0 1 1 1 0	430						
1 1 0 1 0 1 1 1 1	431						

1 1 0 0 1 0 0 0 0	400						
1 1 0 0 1 0 0 0 1	401						
1 1 0 0 1 0 0 1 0	402						
1 1 0 0 1 0 0 1 1	403						
1 1 0 0 1 0 1 0 0	404						
1 1 0 0 1 0 1 0 1	405						
1 1 0 0 1 0 1 1 0	406						
1 1 0 0 1 0 1 1 1	407						

1 1 0 1 1 0 0 0 0	432						
1 1 0 1 1 0 0 0 1	433						
1 1 0 1 1 0 0 1 0	434						
1 1 0 1 1 0 0 1 1	435						
1 1 0 1 1 0 1 0 0	436						
1 1 0 1 1 0 1 0 1	437						
1 1 0 1 1 0 1 1 0	438						
1 1 0 1 1 0 1 1 1	439						

1 1 0 0 1 1 0 0 0	408						
1 1 0 0 1 1 0 0 1	409						
1 1 0 0 1 1 0 1 0	410						
1 1 0 0 1 1 0 1 1	411						
1 1 0 0 1 1 1 0 0	412						
1 1 0 0 1 1 1 0 1	413						
1 1 0 0 1 1 1 1 0	414						
1 1 0 0 1 1 1 1 1	415						

1 1 0 1 1 1 0 0 0	440						
1 1 0 1 1 1 0 0 1	441						
1 1 0 1 1 1 0 1 0	442						
1 1 0 1 1 1 0 1 1	443						
1 1 0 1 1 1 1 0 0	444						
1 1 0 1 1 1 1 0 1	445						
1 1 0 1 1 1 1 1 0	446						
1 1 0 1 1 1 1 1 1	447						

SIGNETICS 64 X 8 X 5 CHARACTER GENERATOR ■ 2513

ADDRESS								DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
A9	A8	A7	A6	A5	A4	A3	A2		A1	05	04	03	02	
1	1	1	0	0	0	0	0	0	448					
1	1	1	0	0	0	0	0	1	449					
1	1	1	0	0	0	0	1	0	450					
1	1	1	0	0	0	0	1	1	451					
1	1	1	0	0	0	1	0	0	452					
1	1	1	0	0	0	1	0	1	453					
1	1	1	0	0	0	1	1	0	454					
1	1	1	0	0	0	1	1	1	455					

ADDRESS								DECIMAL ADDRESS	OUTPUT DATA					USER'S CHAR.
A9	A8	A7	A6	A5	A4	A3	A2		A1	05	04	03	02	
1	1	1	1	0	0	0	0	0	480					
1	1	1	1	0	0	0	0	1	481					
1	1	1	1	0	0	0	1	0	482					
1	1	1	1	0	0	0	1	1	483					
1	1	1	1	0	0	1	0	0	484					
1	1	1	1	0	0	1	0	1	485					
1	1	1	1	0	0	1	1	0	486					
1	1	1	1	0	0	1	1	1	487					

1	1	1	0	0	1	0	0	0	456					
1	1	1	0	0	1	0	0	1	457					
1	1	1	0	0	1	0	1	0	458					
1	1	1	0	0	1	0	1	1	459					
1	1	1	0	0	1	1	0	0	460					
1	1	1	0	0	1	1	0	1	461					
1	1	1	0	0	1	1	1	0	462					
1	1	1	0	0	1	1	1	1	463					

1	1	1	1	0	1	0	0	0	488					
1	1	1	1	0	1	0	0	1	489					
1	1	1	1	0	1	0	1	0	490					
1	1	1	1	0	1	0	1	1	491					
1	1	1	1	0	1	1	0	0	492					
1	1	1	1	0	1	1	0	1	493					
1	1	1	1	0	1	1	1	0	494					
1	1	1	1	0	1	1	1	1	495					

1	1	1	0	1	0	0	0	0	464					
1	1	1	0	1	0	0	0	1	465					
1	1	1	0	1	0	0	1	0	466					
1	1	1	0	1	0	0	1	1	467					
1	1	1	0	1	0	1	0	0	468					
1	1	1	0	1	0	1	0	1	469					
1	1	1	0	1	0	1	1	0	470					
1	1	1	0	1	0	1	1	1	471					

1	1	1	1	1	0	0	0	0	496					
1	1	1	1	1	0	0	0	1	497					
1	1	1	1	1	0	0	1	0	498					
1	1	1	1	1	0	0	1	1	499					
1	1	1	1	1	0	1	0	0	500					
1	1	1	1	1	0	1	0	1	501					
1	1	1	1	1	0	1	1	0	502					
1	1	1	1	1	0	1	1	1	503					

1	1	1	0	1	1	0	0	0	472					
1	1	1	0	1	1	0	0	1	473					
1	1	1	0	1	1	0	1	0	474					
1	1	1	0	1	1	0	1	1	475					
1	1	1	0	1	1	1	0	0	476					
1	1	1	0	1	1	1	0	1	477					
1	1	1	0	1	1	1	1	0	478					
1	1	1	0	1	1	1	1	1	479					

1	1	1	1	1	1	0	0	0	504					
1	1	1	1	1	1	0	0	1	505					
1	1	1	1	1	1	0	1	0	506					
1	1	1	1	1	1	0	1	1	507					
1	1	1	1	1	1	1	0	0	508					
1	1	1	1	1	1	1	0	1	509					
1	1	1	1	1	1	1	1	0	510					
1	1	1	1	1	1	1	1	1	511					

### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

The Signetics 2516 is a 3072-bit Static ROM organized as 64x6x8. The product uses +5V, -5V and -12V power supplies, 5V TTL level input signals and Tri-State outputs for direct, low cost interfacing with TTL, DTL and 2500 Series MOS.

#### FEATURES

- COLUMN OUTPUT (VERTICAL SCAN)
- 450 ns TYPICAL ACCESS TIME
- STATIC OPERATION
- TTL/DTL COMPATIBLE INPUTS
- +5, -5, -12V POWER SUPPLIES
- TRI-STATE OUTPUT
- 2516/CM 2150 ASCII FONT STANDARD (5 x 7)
- 24-PIN DIP PACKAGE
- P-MOS SILICON GATE TECHNOLOGY

#### APPLICATIONS

VERTICAL SCAN CRT DISPLAYS  
 PRINTER CHARACTER GENERATORS  
 PANEL DISPLAYS AND BILLBOARDS  
 MICRO-PROGRAMMING  
 CODE CONVERSION

#### PROCESS TECHNOLOGY

The use of Signetics' unique Silicon Gate Low Threshold Process allows the design and production of higher functional density and operating speed than other techniques.

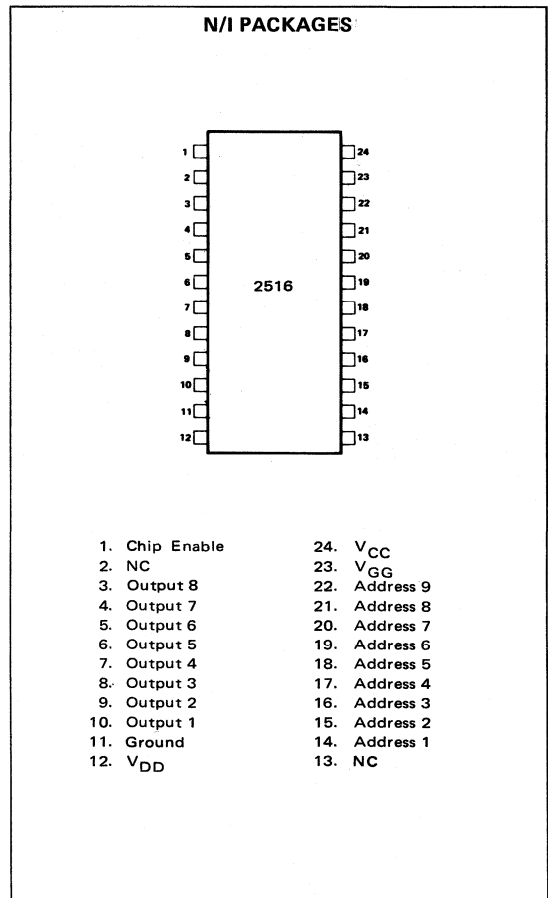
#### BIPOLAR COMPATIBILITY

All inputs of the 2516 can be driven directly by standard bipolar integrated circuits (TTL, DTL, etc.). The data output buffers are capable of sinking a minimum of 1.6mA, sufficient to drive one standard TTL load.

#### SILICONE PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process the silicon material over the gate oxide passivates the MOS transistors. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability, superior moisture resistance, and ionic contamination barriers. For further information reference Signetics - "Silicone Package Qualification Report."

#### PIN CONFIGURATION (Top View)



# SIGNETICS 64 X 6 X 8 STATIC CHARACTER GENERATOR ■ 2516

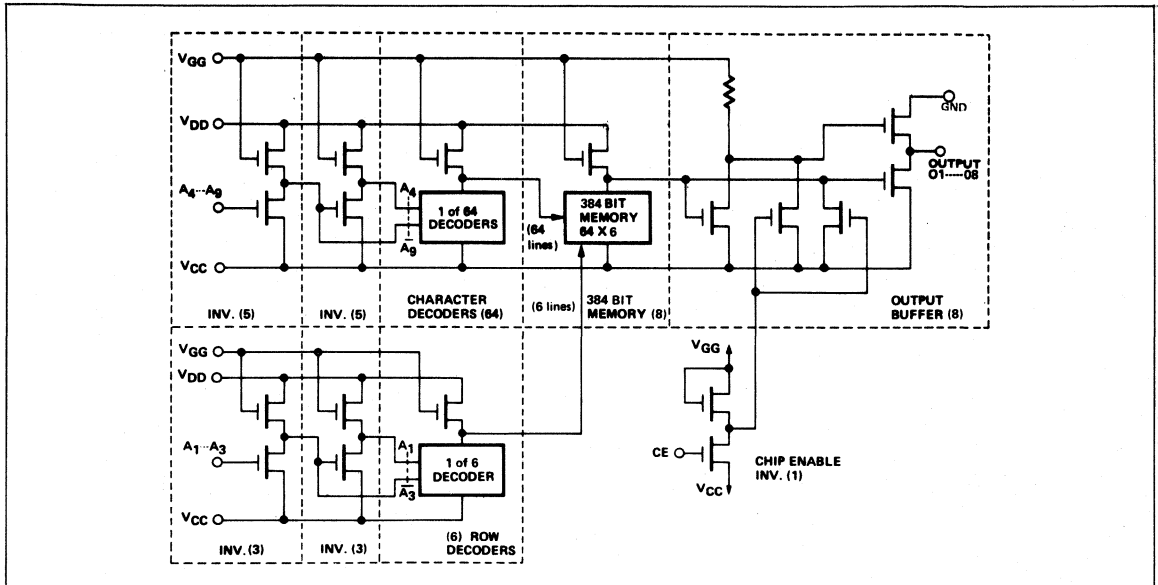
## AC CHARACTERISTICS

$T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ;  $V_{CC} = 5\text{V} \pm 5\%$ ;  $V_{DD} = -5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$ ; unless otherwise noted.

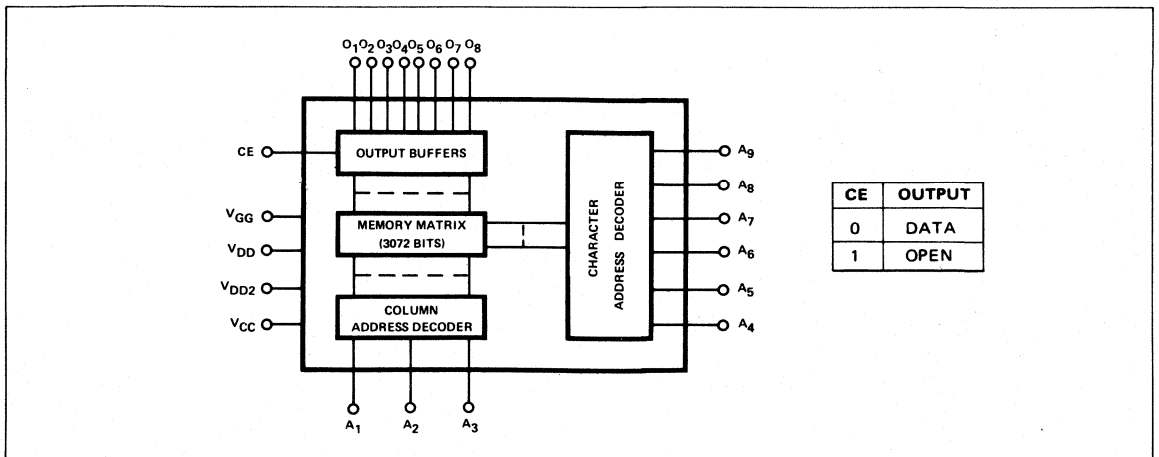
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$V_{OL}$	Output Logic "Zero"	-5		+0.5	V(8)	$I_{OL} = 1.6\text{mA}$
$V_{OH}$	Output Logic "One"	+3.8			V(8)	$I_{OH} = 100\mu\text{A}$
$t_{CA}$	Character Access Time		500	600	ns	See AC Test Setup*
$t_{CA}$	Column Access Time ( $A_1 - A_3$ )		400	500	ns	See AC Test Setup*
$C_{IN}$	Address Input Capacitance			10	pF	$f = 1\text{MHz}$ , $V_{IH} = V_{CC}$ , 25mV p-p

\* $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$

## CIRCUIT SCHEMATIC



## BLOCK DIAGRAM



PART IDENTIFICATION TABLE

PART	ORGANIZATION	PROGRAMMING
2516N/I CM 2150	64 x 6 x 8	ASCII Font
2516N/I CMXXXX	64 x 6 x 8	Custom

N Package = 24 Pin Silicone DIP

I Package = 24 Pin Ceramic DIP

MAXIMUM GUARANTEED RATINGS (1)

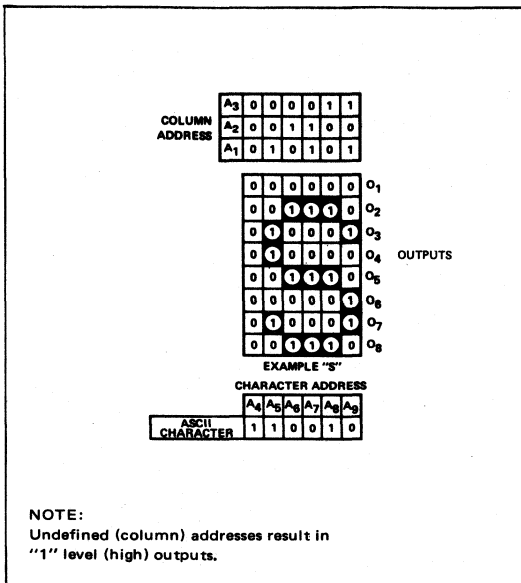
Operating Ambient Temperature 0°C to 70°C

Storage Temperature -65°C to +150°C

Package Power Dissipation<sup>(2)</sup>  
@ 70°C 730 mW

Input<sup>(3)</sup> and Supply Voltages  
with respect to V<sub>CC</sub> +0.3 to -20V

CHARACTER FORMAT



NOTES

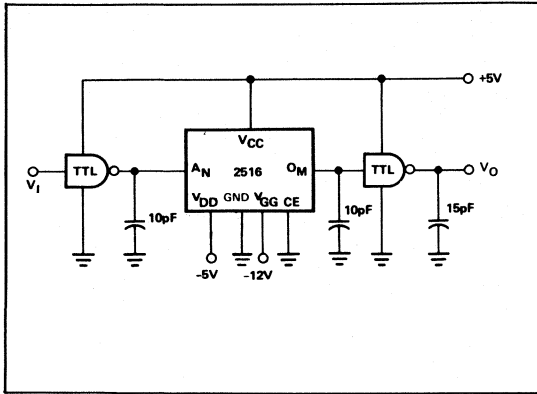
1. Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 110°C/W junction to ambient.
3. All inputs are protected against static charge.
4. Parameters are valid over operating temperature range unless specified.
5. All voltage measurements are referenced to ground.
6. Manufacturer reserves the right to make design and process changes and improvements.
7. Typical values are at +25°C and nominal supply voltages.
8. V<sub>CC</sub> tolerance is ±5%. Any variation in actual V<sub>CC</sub> will be tracked directly by V<sub>IL</sub>, V<sub>IH</sub>, and V<sub>OH</sub> which are stated for a V<sub>CC</sub> of exactly 5 volts.
8. Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.

DC CHARACTERISTICS

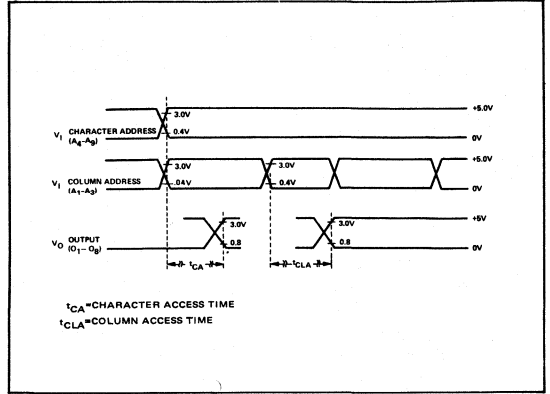
T<sub>A</sub> = 0°C to +70°C; V<sub>CC</sub> = +5V ±5%; V<sub>DD</sub> = -5V ±5%; V<sub>GG</sub> = -12V ±5%; unless otherwise noted. (Notes 4, 5, 6 7)

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current		10	500	nA	V <sub>IN</sub> = -5.5V T <sub>A</sub> = 25°C
I <sub>LO</sub>	Output Leakage Current		10	1000	nA	V <sub>OUT</sub> = -5.5V T <sub>A</sub> = 25°C V <sub>CE</sub> = V <sub>CC</sub>
I <sub>DD</sub>	V <sub>DD</sub> Power Supply Current		14	21	mA	Outputs Open
I <sub>GG</sub>	V <sub>GG</sub> Power Supply Current		8	12	mA	Outputs Open
V <sub>IL</sub>	Input Logic "0"	-5		+0.6	V	Note 8
V <sub>IH</sub>	Input Logic "1"	+3.4		5.3	V	Note 8

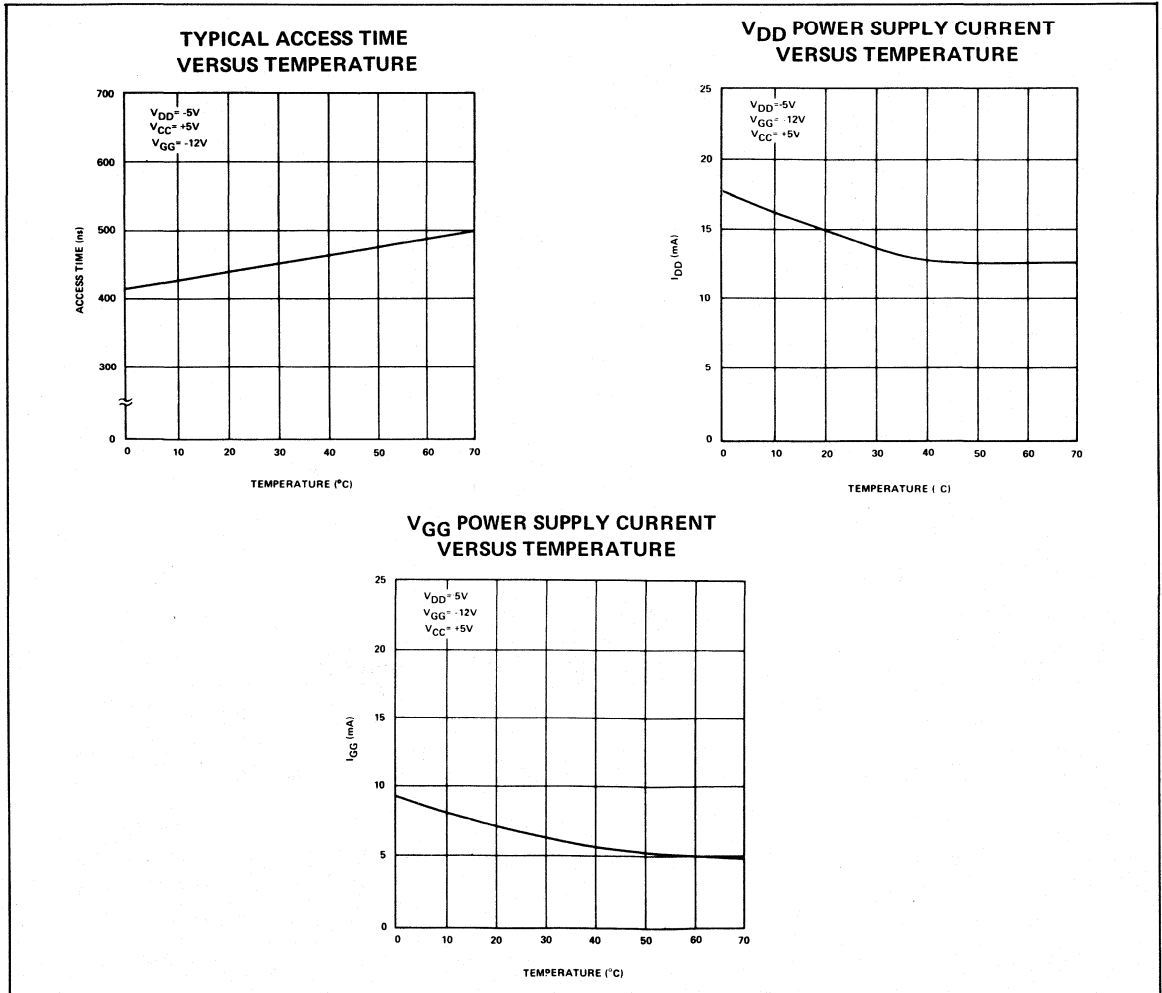
AC TEST SETUP



TIMING DIAGRAM



TYPICAL CHARACTERISTIC CURVES





**APPLICATIONS DATA:****OUTPUT INTERFACING NOTES**

The tri-state outputs on this device exhibit three states:

- "1" — low impedance to +5V
- "0" — low impedance to -5V
- OFF — high impedance >10 megohm

The "off" state is controlled by the chip enable control input.

**CUSTOM ROM ORGANIZATIONS**

The 2516 is a static ROM with a total 64 x 6 x 8 bit capacity. This allows a standard 5 x 7 font to be encoded in the ROM, e.g., the 2516/CM2150 ASCII font standard product. A custom coding configuration may make use of the full 6x8 dot matrix if desired.

**ORGANIZATION AS CHARACTER GENERATOR**

A six-bit binary address ( $A_4$  through  $A_9$ ) selects 1-of-64 matrix characters arranged 6 dots horizontally and 8 dots vertically. A three bit-binary address code ( $A_1$  through  $A_3$ ) selects 1 of 6 columns. Eight outputs display a complete column of the character matrix.

**STANDARD PATTERN**

A standard ASCII Character Font is available for the 2516. This device (2516N / CM2150) may be used for ASCII character generation or for device evaluation.

**CUSTOM DEVICES**

For unique custom memory patterns, the following formats should be used to transmit coding instructions. The nomenclature for each custom device will consist of the basic product type followed by a unique "CM" number assigned by Signetics. For example, "2516N/CM2151",

- **Programming with punched cards.**  
For maximum accuracy and minimum cost and turn-around time, the truth table should be transmitted to Signetics in the form of punched cards according to the format indicated on the following pages.
- **Programming with written truth table.**  
When punched data cards cannot be supplied, the truth table may be transmitted in written form using the attached blank truth table.

**VERIFICATION**

Upon receipt of either punched card or written truth table information, Signetics will prepare a computer tabulation of the instructions and return to the address indicated. If errors are detected, they should be transmitted to Signetics as quickly as possible.

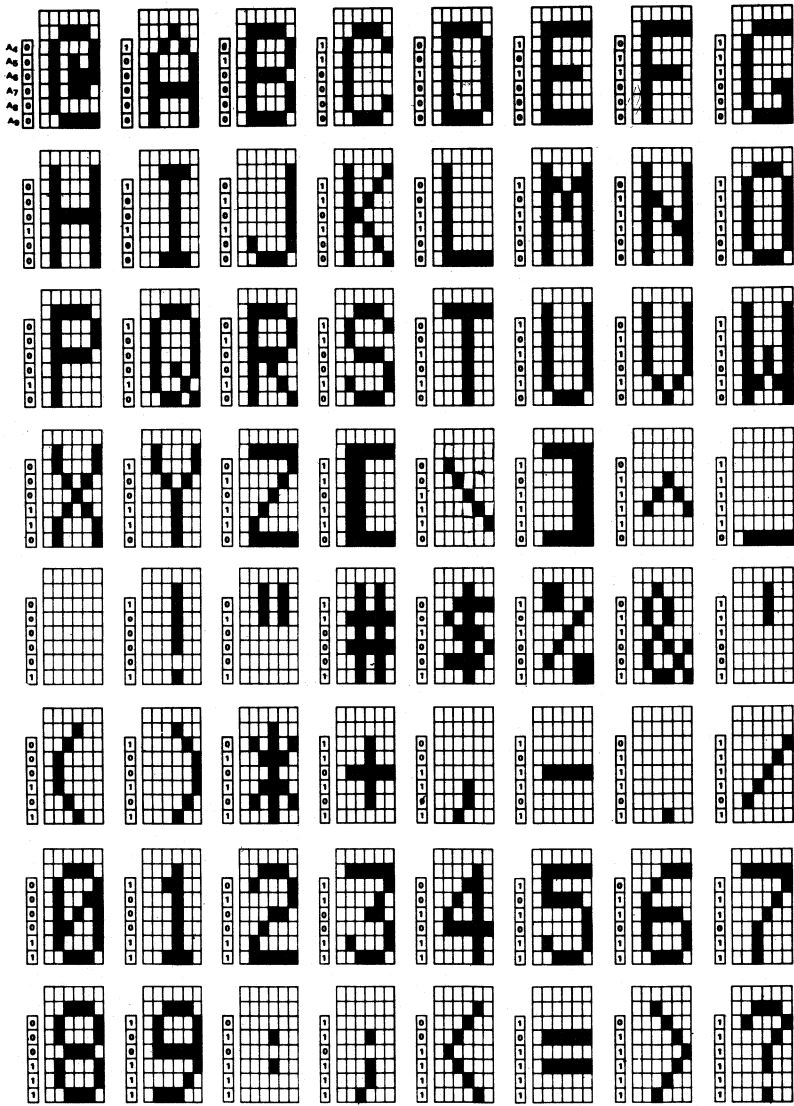
**LOGIC CONVENTION**

Logic "1"s or blackened squares in the truth table will result in "high" output from the indicated output terminal (i.e. +3.6V minimum). Similarly, a "1" address input level is interpreted as +3.2V minimum.

Undefined addresses result in "1" level outputs.

ASCII CHARACTER FONT

2516N/CM2150



NOTE: Excess addresses yield logic "1" outputs.





SIGNETICS 64 X 6 X 8 STATIC CHARACTER GENERATOR ■ 2516

Character Number 001						
Column Binary	Column Decimal Address					
	000	001	002	003	004	005
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Character Number 002						
Column Binary	Column Decimal Address					
	008	009	010	011	012	013
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Character Number 003						
Column Binary	Column Decimal Address					
	016	017	018	019	020	021
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Character Number 004						
Column Binary	Column Decimal Address					
	024	025	026	027	028	029
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Character Number 005						
Column Binary	Column Decimal Address					
	032	033	034	035	036	037
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Character Number 006						
Column Binary	Column Decimal Address					
	040	041	042	043	044	045
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Character Number 007						
Column Binary	Column Decimal Address					
	048	049	050	051	052	053
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Character Number 008						
Column Binary	Column Decimal Address					
	056	057	058	059	060	061
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	0	0	0	0	0	0

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

Output	Output Codes					
01						
02						
03						
04						
05						
06						
07						
08						

**SIGNETICS 64 X 6 X 8 STATIC CHARACTER GENERATOR ■ 2516**

Character Number <b>009</b>							
Column Binary	Column Decimal Address						
	064	065	066	067	068	069	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	0	0	0	0	0	0	
A5	0	0	0	0	0	0	
A6	0	0	0	0	0	0	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Character Number <b>010</b>							
Column Binary	Column Decimal Address						
	072	073	074	075	076	077	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	1	1	1	1	1	1	
A5	0	0	0	0	0	0	
A6	0	0	0	0	0	0	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Character Number <b>011</b>							
Column Binary	Column Decimal Address						
	080	081	082	083	084	085	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	0	0	0	0	0	0	
A5	1	1	1	1	1	1	
A6	0	0	0	0	0	0	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Character Number <b>012</b>							
Column Binary	Column Decimal Address						
	088	089	090	091	092	093	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	1	1	1	1	1	1	
A5	1	1	1	1	1	1	
A6	0	0	0	0	0	0	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Output	Output Codes						
01							
02							
03							
04							
05							
05							
07							
08							

Output	Output Codes						
01							
02							
03							
04							
05							
05							
07							
08							

Output	Output Codes						
01							
02							
03							
04							
05							
05							
07							
08							

Output	Output Codes						
01							
02							
03							
04							
05							
05							
07							
08							

Character Number <b>013</b>							
Column Binary	Column Decimal Address						
	096	097	098	099	100	101	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	0	0	0	0	0	0	
A5	0	0	0	0	0	0	
A6	1	1	1	1	1	1	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Character Number <b>014</b>							
Column Binary	Column Decimal Address						
	104	105	106	107	108	109	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	1	1	1	1	1	1	
A5	0	0	0	0	0	0	
A6	1	1	1	1	1	1	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Character Number <b>015</b>							
Column Binary	Column Decimal Address						
	112	113	114	115	116	117	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	0	0	0	0	0	0	
A5	1	1	1	1	1	1	
A6	1	1	1	1	1	1	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

Character Number <b>016</b>							
Column Binary	Column Decimal Address						
	120	121	122	123	124	125	
A1	0	1	0	1	0	1	
A2	0	0	1	1	0	0	
A3	0	0	0	0	1	1	
A4	1	1	1	1	1	1	
A5	1	1	1	1	1	1	
A6	1	1	1	1	1	1	
A7	1	1	1	1	1	1	
A8	0	0	0	0	0	0	
A9	0	0	0	0	0	0	

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Character Number <b>017</b>						
Column Binary Address	Column Decimal Address					
	128	129	130	131	132	133
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>018</b>						
Column Binary Address	Column Decimal Address					
	136	137	138	139	140	141
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>019</b>						
Column Binary Address	Column Decimal Address					
	144	145	146	147	148	149
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>020</b>						
Column Binary Address	Column Decimal Address					
	152	153	154	155	156	157
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Output	Output Codes					
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Character Number <b>021</b>						
Column Binary Address	Column Decimal Address					
	160	161	162	163	164	165
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>022</b>						
Column Binary Address	Column Decimal Address					
	168	169	170	171	172	173
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>023</b>						
Column Binary Address	Column Decimal Address					
	176	177	178	179	180	181
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>024</b>						
Column Binary Address	Column Decimal Address					
	184	185	186	187	188	189
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

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Character Number <b>025</b>						
Column Binary Address	Column Decimal Address					
	192	193	194	195	196	197
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>026</b>						
Column Binary Address	Column Decimal Address					
	200	201	202	203	204	205
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>027</b>						
Column Binary Address	Column Decimal Address					
	208	209	210	211	212	213
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>028</b>						
Column Binary Address	Column Decimal Address					
	216	217	218	219	220	221
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Output	Output Codes					
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Character Number <b>029</b>						
Column Binary Address	Column Decimal Address					
	224	225	226	227	228	229
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>030</b>						
Column Binary Address	Column Decimal Address					
	232	233	234	235	236	237
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>031</b>						
Column Binary Address	Column Decimal Address					
	240	241	242	243	244	245
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

Character Number <b>032</b>						
Column Binary Address	Column Decimal Address					
	248	249	250	251	252	253
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	0	0	0	0	0	0

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Character Number <b>033</b>						
Column Binary	Column Decimal Address					
	256	257	258	259	260	261
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>034</b>						
Column Binary	Column Decimal Address					
	264	265	266	267	268	269
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>035</b>						
Column Binary	Column Decimal Address					
	272	273	274	275	276	277
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>036</b>						
Column Binary	Column Decimal Address					
	280	281	282	283	284	285
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Output	Output Codes					
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Character Number <b>037</b>						
Column Binary	Column Decimal Address					
	288	289	290	291	292	293
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>038</b>						
Column Binary	Column Decimal Address					
	296	297	298	299	300	301
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>039</b>						
Column Binary	Column Decimal Address					
	304	305	306	307	308	309
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>040</b>						
Column Binary	Column Decimal Address					
	312	313	314	315	316	317
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

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Character Number <b>041</b>						
Column Binary	Column Decimal Address					
	320	321	322	323	324	325
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>042</b>						
Column Binary	Column Decimal Address					
	328	329	330	331	332	333
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>043</b>						
Column Binary	Column Decimal Address					
	336	337	338	339	340	341
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>044</b>						
Column Binary	Column Decimal Address					
	344	345	346	347	348	349
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Output	Output Codes					
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Character Number <b>045</b>						
Column Binary	Column Decimal Address					
	352	353	354	355	356	357
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>046</b>						
Column Binary	Column Decimal Address					
	360	361	362	363	364	365
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>047</b>						
Column Binary	Column Decimal Address					
	368	369	370	371	372	373
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

Character Number <b>048</b>						
Column Binary	Column Decimal Address					
	376	377	378	379	380	381
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	0	0	0	0	0	0
A9	1	1	1	1	1	1

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Character Number <b>049</b>						
Column Binary Address	Column Decimal Address					
	384	385	386	387	388	389
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>050</b>						
Column Binary Address	Column Decimal Address					
	392	393	394	395	396	397
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>051</b>						
Column Binary Address	Column Decimal Address					
	400	401	402	403	404	405
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>052</b>						
Column Binary Address	Column Decimal Address					
	408	409	410	411	412	413
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Output	Output Codes					
01						
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03						
04						
05						
05						
07						
08						

Output	Output Codes					
01						
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Output	Output Codes					
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Output	Output Codes					
01						
02						
03						
04						
05						
05						
07						
08						

Character Number <b>053</b>						
Column Binary Address	Column Decimal Address					
	416	417	418	419	420	421
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>054</b>						
Column Binary Address	Column Decimal Address					
	424	425	426	427	428	429
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>055</b>						
Column Binary Address	Column Decimal Address					
	432	433	434	435	436	437
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>056</b>						
Column Binary Address	Column Decimal Address					
	440	441	442	443	444	445
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	0	0	0	0	0	0
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Output	Output Codes					
01						
02						
03						
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Output	Output Codes					
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Output	Output Codes					
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Output	Output Codes					
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08						

**SIGNETICS 64 X 6 X 8 STATIC CHARACTER GENERATOR ■ 2516**

Character Number <b>057</b>						
Column Binary	Column Decimal Address					
	448	449	450	451	452	453
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>058</b>						
Column Binary	Column Decimal Address					
	456	457	458	459	460	461
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>059</b>						
Column Binary	Column Decimal Address					
	464	465	466	467	468	469
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>060</b>						
Column Binary	Column Decimal Address					
	472	473	474	475	476	477
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	0	0	0	0	0	0
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Output	Output Codes					
01						
02						
03						
04						
05						
05						
07						
08						

Output	Output Codes					
01						
02						
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Output	Output Codes					
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Output	Output Codes					
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Character Number <b>061</b>						
Column Binary	Column Decimal Address					
	480	481	482	483	484	485
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>062</b>						
Column Binary	Column Decimal Address					
	488	489	490	491	492	493
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	0	0	0	0	0	0
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>063</b>						
Column Binary	Column Decimal Address					
	496	497	498	499	500	501
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	0	0	0	0	0	0
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Character Number <b>064</b>						
Column Binary	Column Decimal Address					
	504	505	506	507	508	509
A1	0	1	0	1	0	1
A2	0	0	1	1	0	0
A3	0	0	0	0	1	1
A4	1	1	1	1	1	1
A5	1	1	1	1	1	1
A6	1	1	1	1	1	1
A7	1	1	1	1	1	1
A8	1	1	1	1	1	1
A9	1	1	1	1	1	1

Output	Output Codes					
01						
02						
03						
04						
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Output	Output Codes					
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Output	Output Codes					
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Output	Output Codes					
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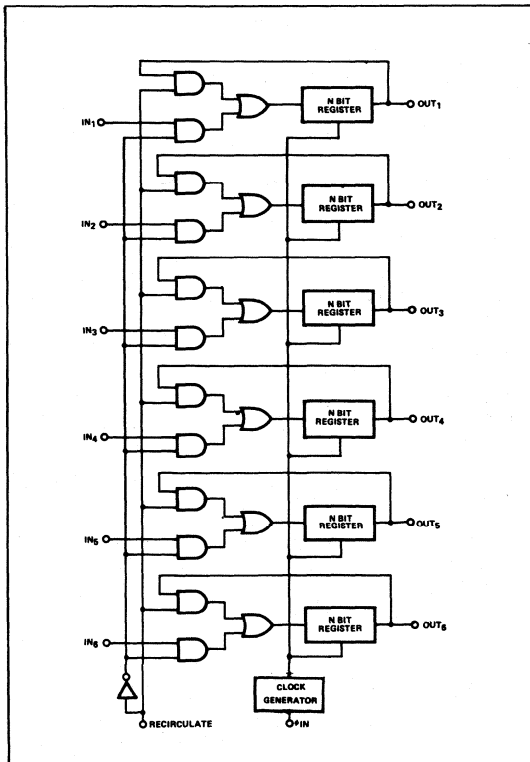
#### DESCRIPTION

These Signetics 2500 Series hex 32-bit and hex 40-bit recirculating static shift registers consist of enhancement mode P-channel silicon gate MOS devices integrated on a single monolithic chip. Internal recirculation logic plus TTL/DTL level clock signals are provided for maximum interfacing ease.

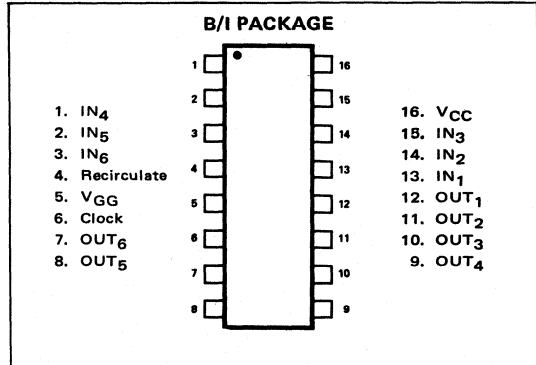
#### FEATURES

- TYPICAL CLOCK AND DATA RATE = 3MHz
- SINGLE TTL/DTL COMPATIBLE CLOCK
- LOW CLOCK CAPACITANCE
- RECIRCULATION PATH ON CHIP
- TWO BIT LENGTHS AVAILABLE
- SINGLE-ENDED (BARE DRAIN) BUFFERS
- TTL, DTL COMPATIBLE SIGNALS
- STANDARD PACKAGE – 16 PIN DIP
- P-MOS SILICON GATE TECHNOLOGY

#### BLOCK DIAGRAM



#### PIN CONFIGURATIONS (Top View)



#### APPLICATIONS

- LOW COST SEQUENTIAL ACCESS MEMORIES
- LOW COST STATIC BUFFER MEMORIES
- CRT REFRESH MEMORIES – LINE STORAGE
- LINE PRINTERS
- CARD EQUIPMENT BUFFERS

#### TRUTH TABLE

RECIRCULATE	INPUT	FUNCTION
1	0	Recirculate
1	1	Recirculate
0	0	"0" is Written
0	1	"1" is Written

#### PART IDENTIFICATION TABLE

PART NUMBER	BIT LENGTH	PACKAGE
2518B	HEX 32	16-Pin Silicone DIP
2518I	HEX 32	16-Pin Ceramic DIP
2519B	HEX 40	16-Pin Silicone DIP
2519I	HEX 40	16-Pin Ceramic DIP

**MAXIMUM GUARANTEED RATINGS (1)**

Operating Temperature (2)	0°C to +70°C
Storage Temperature	-65°C to +150°C
Package Power Dissipation at T <sub>A</sub> = 70°C	640 mW
Data and Clock Input Voltages and Supply Voltages with Respect to V <sub>CC</sub>	+0.3V to -20V

**NOTES**

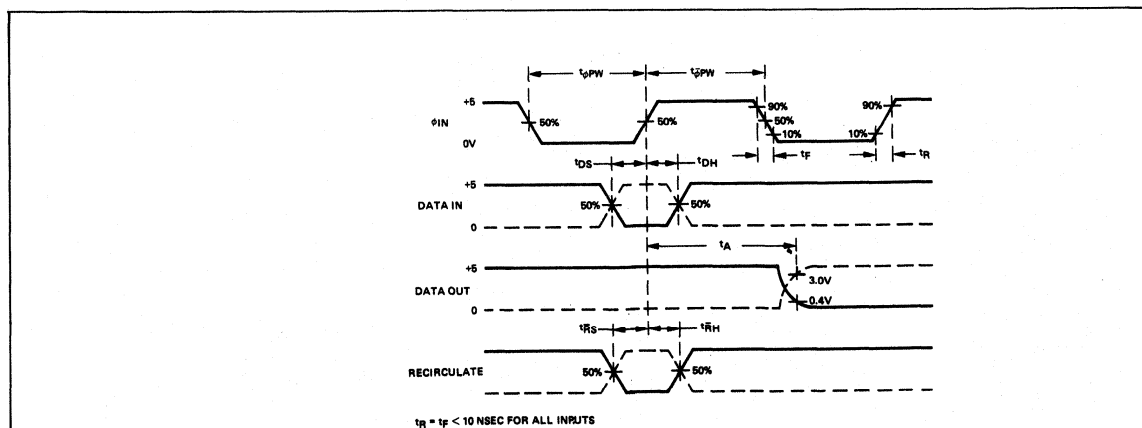
1. Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a 150°C maximum junction temperature and a thermal resistance of 125°C C/W<sub>junction</sub> to ambient.
3. All inputs are protected against static charge.
4. Parameters are valid over operating temperature range unless specified.
5. All voltage measurements are referenced to ground.
6. Manufacturer reserves the right to make design and process changes and improvements.
7. Typical values are at +25°C and nominal supply voltages.
8. Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.
9. V<sub>OL</sub> is dependent on R<sub>L</sub> and input characteristics of driven gate.

**DC CHARACTERISTICS**

T<sub>A</sub> = 0°C to +70°C; V<sub>CC</sub> = +5V ±5%; V<sub>GG</sub> = -12V ±5% unless otherwise noted. (Notes: 3,4,5,6,7)

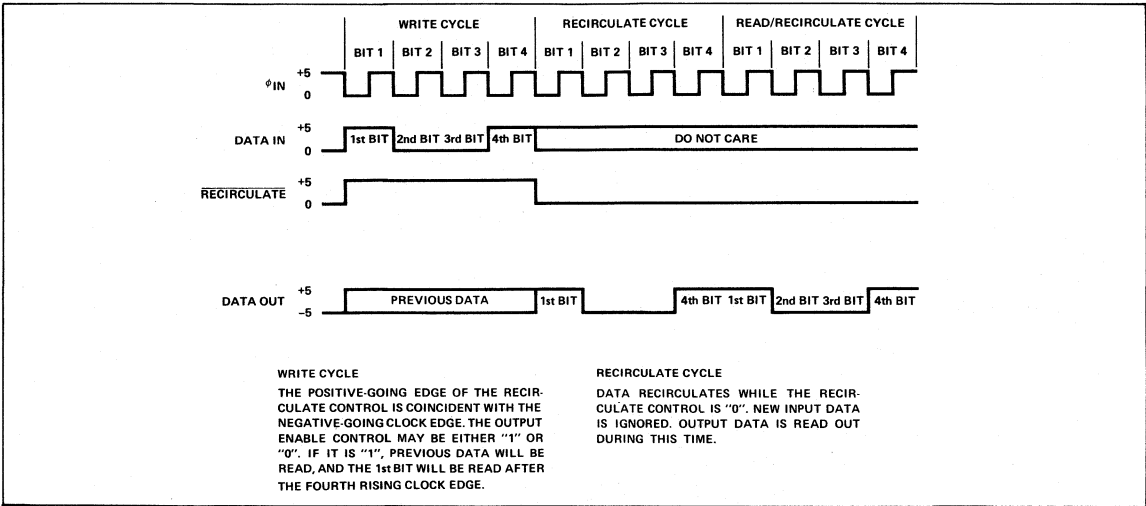
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
I <sub>LI</sub>	INPUT LOAD CURRENT		10	500	nA	V <sub>in</sub> = -5.5V, T <sub>A</sub> = 25°C
I <sub>LO</sub>	OUTPUT LEAKAGE CURRENT		10	1000	nA	T <sub>A</sub> = 25°C
I <sub>LC</sub>	CLOCK LEAKAGE CURRENT		10	500	nA	V <sub>ILC</sub> = GND, T <sub>A</sub> = 25°C
I <sub>GG</sub>	POWER SUPPLY CURRENT		16	25	mA	CONTINUOUS OPERATION T <sub>A</sub> = 25°C F = 1.5 MHz
V <sub>IL</sub>	INPUT "LOW" VOLTAGE			+0.6	V	Note 8
V <sub>IH</sub>	INPUT "HIGH" VOLTAGE	+3.4		5.3	V	Note 8
V <sub>ILC</sub>	CLOCK INPUT "LOW" VOLTAGE			+0.6	V	Note 8
V <sub>IHC</sub>	CLOCK INPUT "HIGH" VOLTAGE	+3.4		5.3	V	Note 8

**TIMING DIAGRAM**



- NOTES: A. Input rise and fall times: 10nsec. Output load is 1 TTL gate.  
 B. For static operation, clock must be stopped in TTL "1" state in order to retain data (see clock pulse width specification).

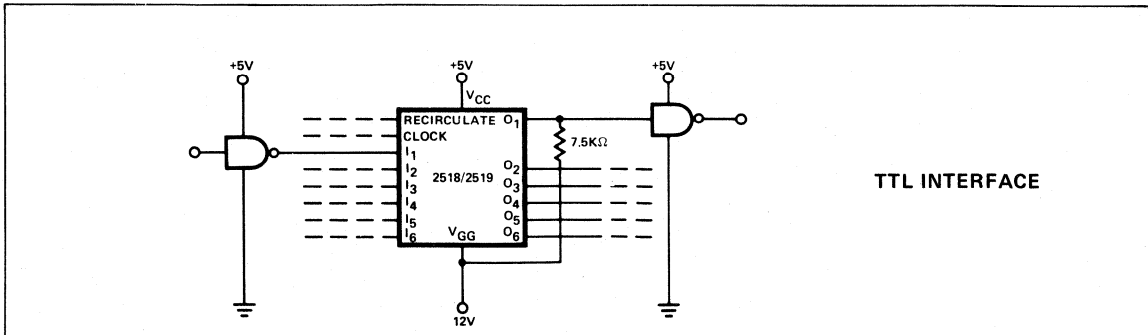
TIMING DIAGRAM



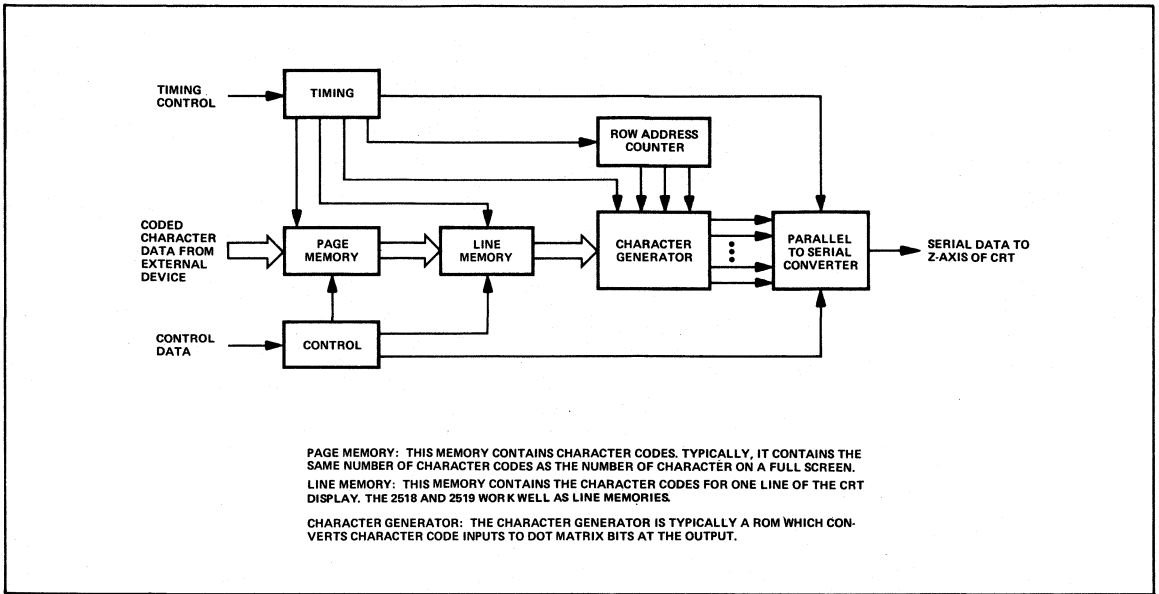
**AC CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$ ,  $V_{ILC} = 0.4\text{V}$  to  $4.0\text{V}$

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
FREQUENCY	CLOCK REP RATE	DC	3	2	MHz	See Max Frequency Curve
$t_{\phi PW}$	CLOCK PULSE WIDTH	.300		100	$\mu\text{sec}$	See Note B
$t_{\phi PW}$	CLOCK PULSE WIDTH	.200		DC	$\mu\text{sec}$	
$t_R, t_F$	CLOCK PULSE TRANSITION			5	$\mu\text{sec}$	
$t_{DS}$	DATA WRITE (SET-UP) TIME	100			nsec	
$t_{DH}$	DATA TO CLOCK HOLD TIME	50			nsec	
$t_A$	CLOCK TO DATA OUT DELAY		300	350	nsec	
$t_{RS}$	RECIRCULATE SET-UP TIME	150			ns	
$t_{RH}$	RECIRCULATE HOLD TIME	50			ns	
$C_{in}$	INPUT CAPACITANCE		5	7	pF	@ 1MHz; $V_{in} = V_{CC}$ ; $V_{AC} = 25\text{mV p-p}$
$C_{\phi}$	CLOCK CAPACITANCE		6	7	pF	@ 1MHz; $V_{\phi} = V_{CC}$ ; $V_{AC} = 25\text{mV p-p}$
$V_{OL}$	OUTPUT "LOW" VOLTAGE		+0.5		V	$I_{OL} = 1.6\text{mA}$
$V_{OH}$	OUTPUT "HIGH" VOLTAGE	+3.8			V	$I_{OH} = 100\mu\text{A}$

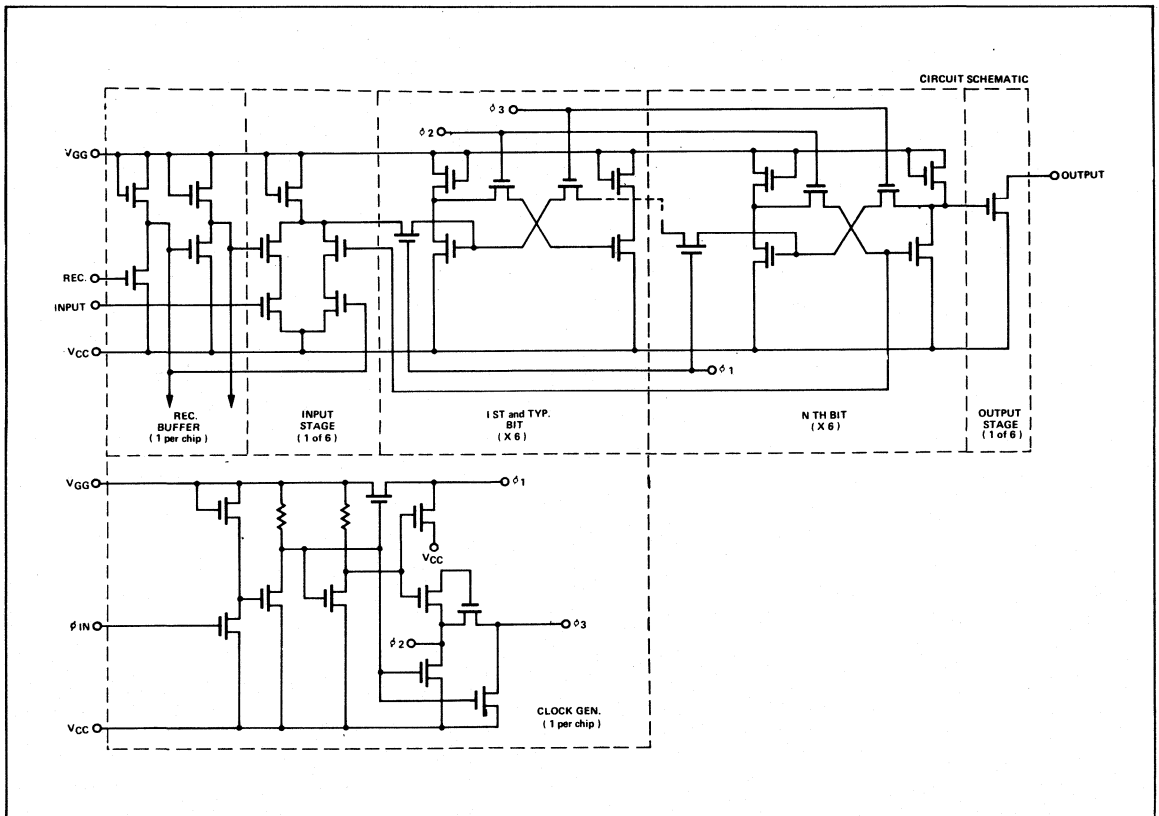
APPLICATIONS DATA



APPLICATIONS (Cont'd)



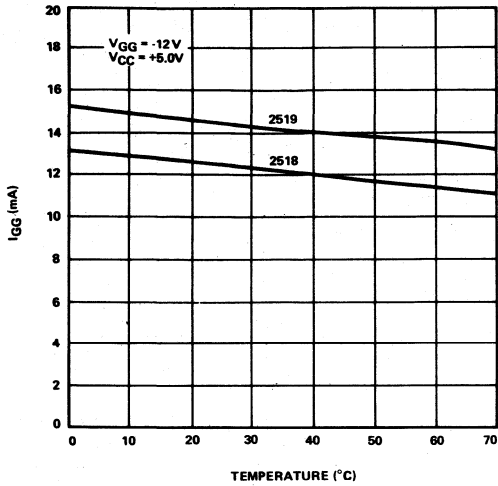
CIRCUIT SCHEMATIC



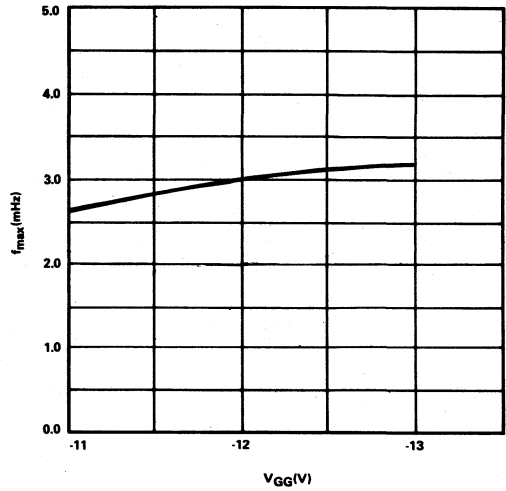


TYPICAL CHARACTERISTIC CURVES

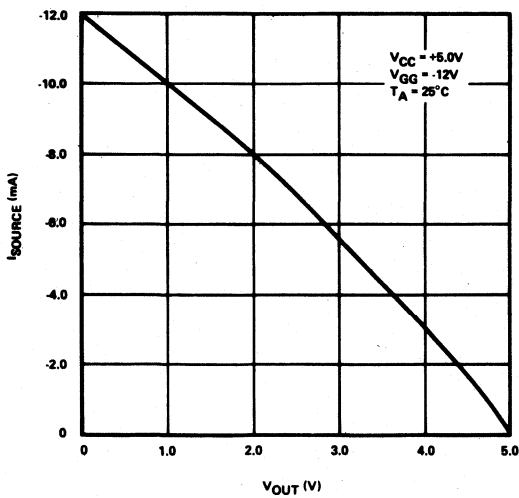
$I_{GG}$  VERSUS TEMPERATURE



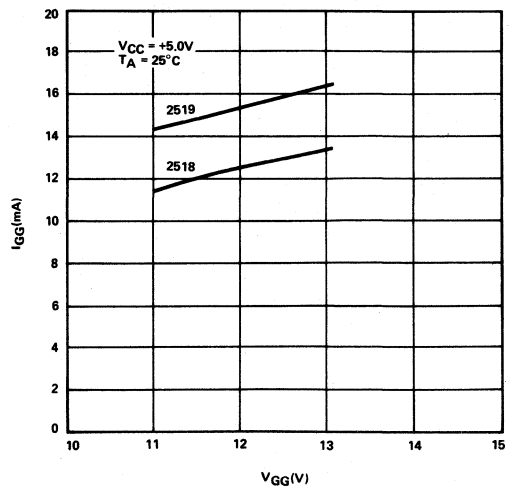
MAXIMUM SHIFT FREQUENCY  
VERSUS  $V_{GG}$



$I_{SOURCE}$  VERSUS  $V_{OUT}$



$I_{GG}$  VERSUS  $V_{GG}$



### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

These Signetics 2500 Series Dual 128 and 132 bit recirculating static shift registers consist of enhancement mode P-channel silicon gate MOS devices integrated on a single monolithic chip.

#### FEATURES

- PUSH-PULL OUTPUTS
- TTL/DTL COMPATIBLE CLOCK
- LOW CLOCK CAPACITANCE
- RECIRCULATION PATH ON CHIP
- TWO BIT LENGTHS AVAILABLE
- HIGH FREQUENCY OPERATION – 1.5MHz TYPICAL
- TTL, DTL COMPATIBLE SIGNALS
- STANDARD PACKAGE – 8 LEAD SILICONE DIP
- P-MOS SILICON GATE TECHNOLOGY

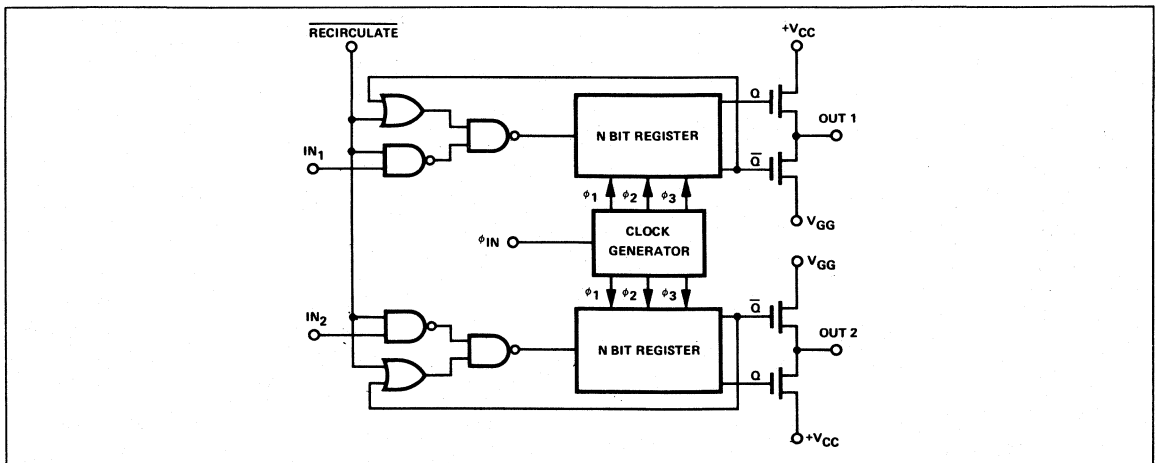
#### APPLICATIONS

SEQUENTIAL ACCESS MEMORIES  
 STATIC BUFFER MEMORIES  
 CRT REFRESH MEMORIES  
 LINE PRINTERS

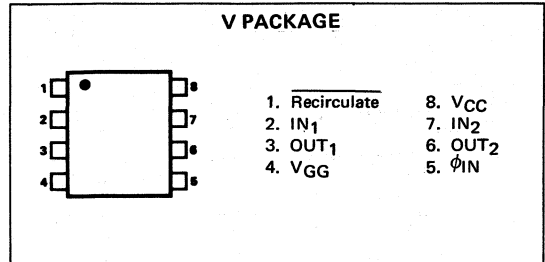
#### BIPOLAR COMPATIBILITY

The clock and signal inputs of these registers can be driven directly by standard bipolar integrated (TTL, DTL, etc.) or by MOS circuits.

#### BLOCK DIAGRAM



#### PIN CONFIGURATION (Top View)



#### TRUTH TABLE

RECIRCULATE	INPUT	FUNCTION
0	0	Recirculate
0	1	Recirculate
1	0	"0" is Written
1	1	"1" is Written

NOTE: "0" = 0V; "1" = +5V.

#### PART IDENTIFICATION TABLE

PART NUMBER	BIT LENGTH	PACKAGE
2521V	Dual 128	8 Pin DIP
2522V	Dual 132	8 Pin DIP

# SIGNETICS HEX 32-BIT AND HEX 40-BIT STATIC SHIFT REGISTERS ■ 2518, 2519

## MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature (2)	0°C to +70°C
Storage Temperature	-65°C to +150°C
Package Power Dissipation at $T_A = 70^\circ\text{C}$	535 mW
Data and Clock Input Voltages and Supply Voltages with respect to $V_{CC}$	+0.3V to -20V

## NOTES:

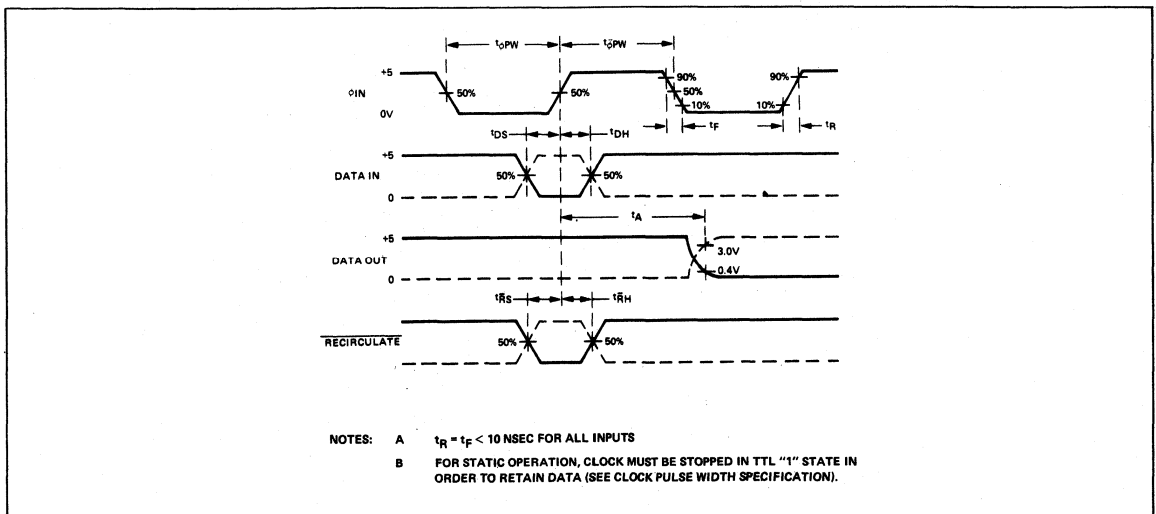
1. Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W junction to ambient.
3. All inputs are protected against static charge.
4. Parameters are valid over operating temperature range unless specified.
5. All voltage measurements are referenced to ground.
6. Manufacturer reserving the right to make design and process changes and improvements.
7. Typical values are at +25°C and nominal supply voltages.
8. Guaranteed input levels are stated for worst case conditions including a ±5% variation in  $V_{CC}$  and a temperature variation of 0°C to +70°C. Actual input requirements with respect to  $V_{CC}$  are  $V_{IH} = V_{CC} - 1.85\text{V}$  and  $V_{IL} = V_{CC} - 4.15\text{V}$ .

**DC CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to +70°C;  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$  unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$I_{LI}$	INPUT LOAD CURRENT		10	500	nA	$V_{in} = 5.5\text{V}$ , $T_A = 25^\circ\text{C}$ $V_{ILC} = \text{GND}$ , $T_A = 25^\circ\text{C}$ CONTINUOUS OPERATION $F = 1.5\text{MHz}$ , $T_A = 25^\circ\text{C}$
$I_{LC}$	CLOCK LEAKAGE CURRENT		10	500	nA	
$I_{GG}$	POWER SUPPLY CURRENT		28	32	mA	
$V_{IL}$	INPUT "LOW" VOLTAGE			0.6V	V	See Note 8
$V_{IH}$	INPUT "HIGH" VOLTAGE	+3.4		5.3	V	
$V_{ILC}$	CLOCK INPUT "LOW" VOLTAGE			0.6V	V	
$V_{IHC}$	CLOCK INPUT "HIGH" VOLTAGE	+3.4		5.3	V	

**CONDITIONS OF TEST** Input rise and fall times: 10 nsec. Output load is 1 TTL gate

## TIMING DIAGRAM

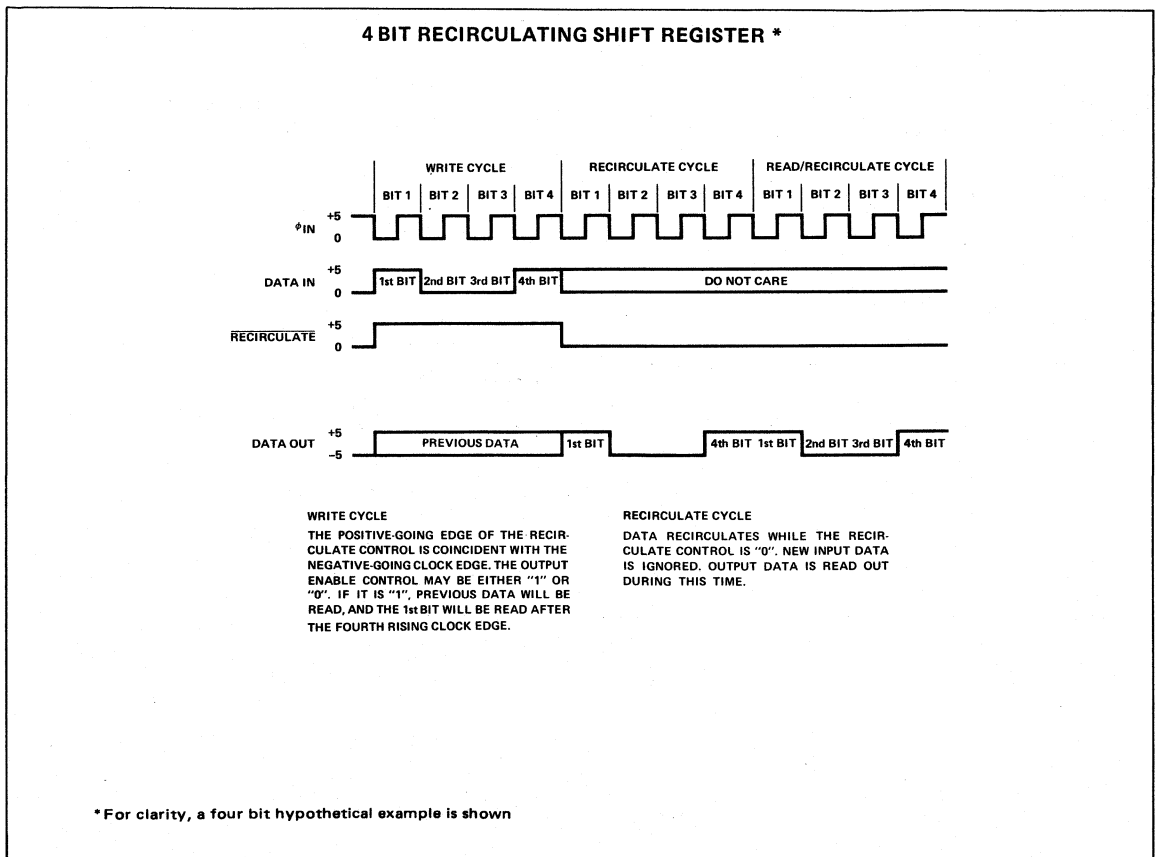


# SIGNETICS DUAL 128-BIT/DUAL 132-BIT STATIC SHIFT REGISTERS ■ 2521, 2522

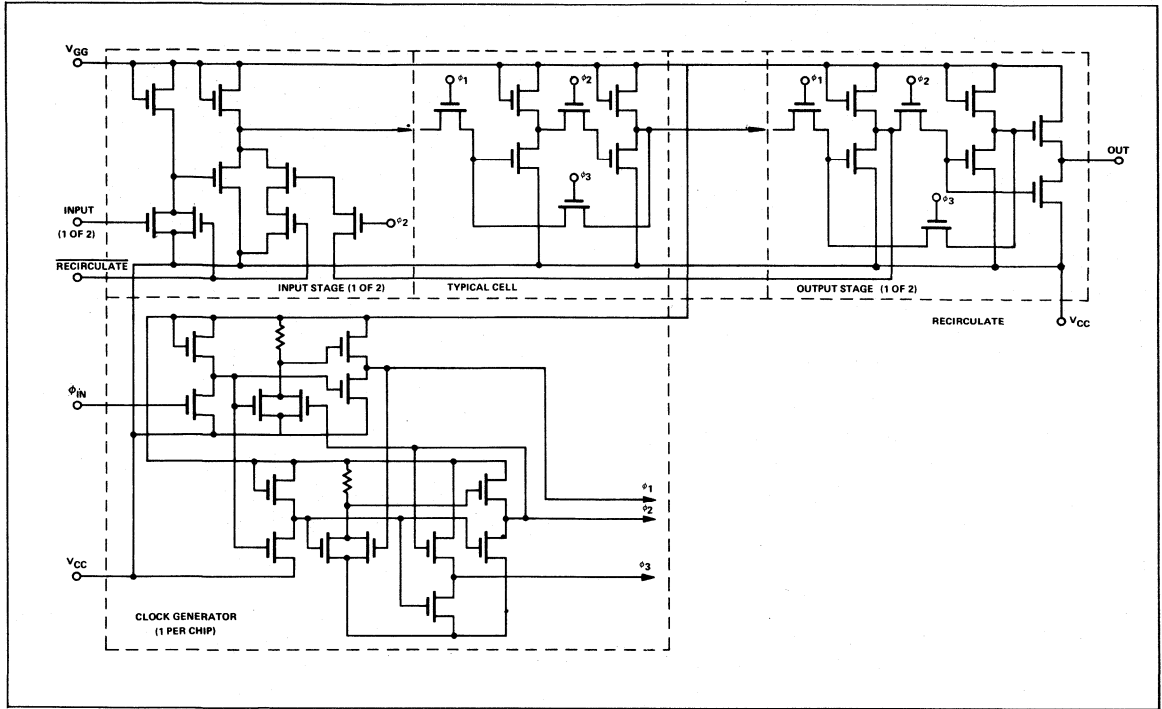
AC CHARACTERISTICS  $V_{CC} = +5V \pm 5\%$ ;  $V_{GG} = -12V \pm 5\%$ ;  $T_A = 0^\circ$  to  $+70^\circ C$

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
FREQUENCY	CLOCK REP RATE	DC		1.5	MHz	See Maximum Frequency Curve See Note B  @ 1MHz; $V_{in} = V_{CC}$ ; $V_{AC} = 25mV$ p-p @ 1MHz; $V_{\phi} = V_{CC}$ ; $V_{AC} = 25mV$ p-p $I_{OL} = 1.6mA$  $I_{OH} = 100\mu A$
$t_{\phi PW}$	CLOCK PULSE WIDTH	.350	.100	100	$\mu sec$	
$t_{\phi PW}$	CLOCK PULSE WIDTH	.200		DC	$\mu sec$	
$t_R, t_F$	CLOCK PULSE TRANSITION			1	usec	
$t_{DS}$	DATA WRITE (SET-UP) TIME	75			nsec	
$t_{DH}$	DATA TO CLOCK HOLD TIME	50			nsec	
$t_A$	CLOCK TO DATA OUT DELAY		250	350	nsec	
$t_{RS}$	RECIRCULATE SET-UP TIME	50			ns	
$t_{RH}$	RECIRCULATE HOLD TIME	50			ns	
$C_{IN}$	INPUT CAPACITANCE			5	pF	
$C_{\phi}$	CLOCK CAPACITANCE			5	pF	
$V_{OL}$	OUTPUT "LOW" VOLTAGE			+0.5	V	
$V_{OH}$	OUTPUT "HIGH" VOLTAGE	+3.8			V	

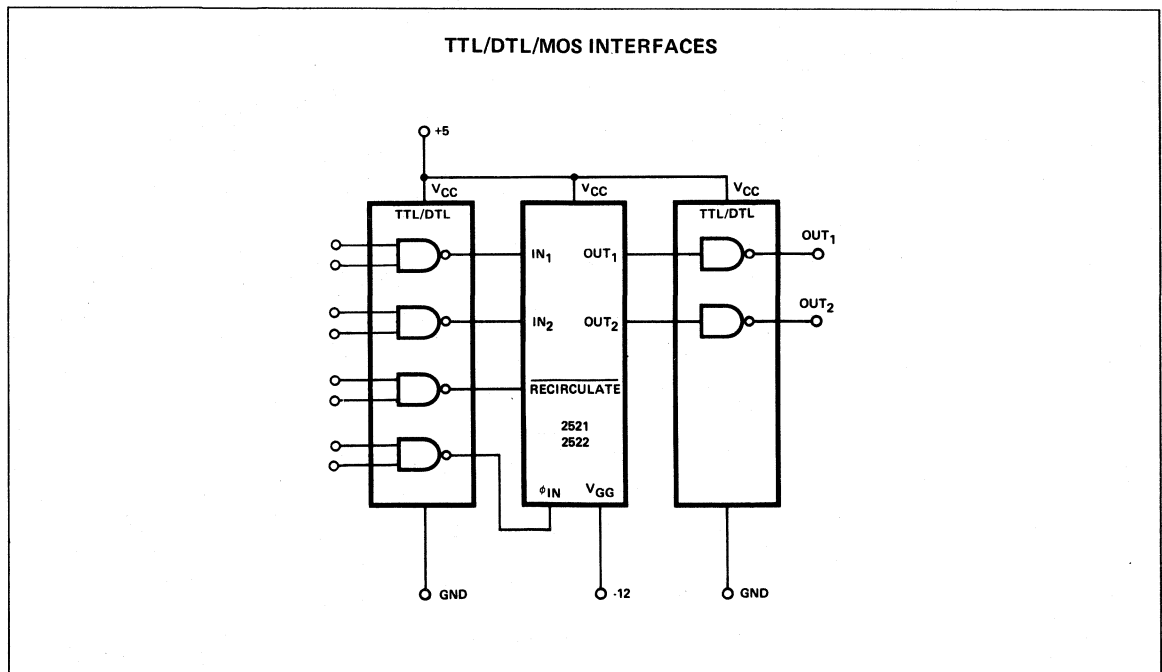
## EXAMPLE TIMING DIAGRAM FOR 4-BIT SHIFT REGISTER



**SCHEMATIC DIAGRAM**

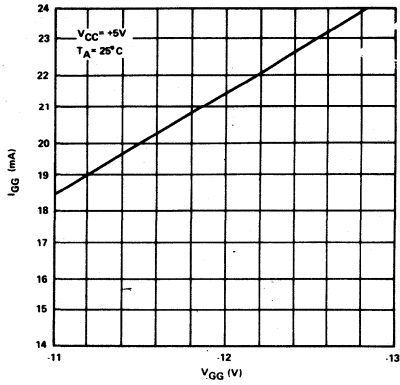


**APPLICATIONS DATA**

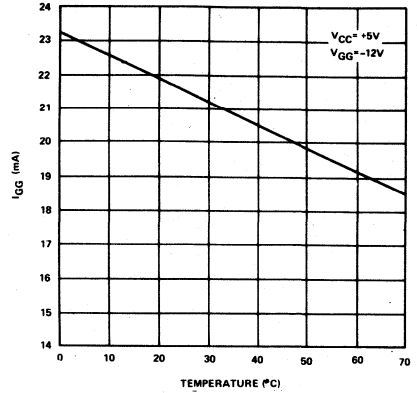


TYPICAL CHARACTERISTIC CURVES

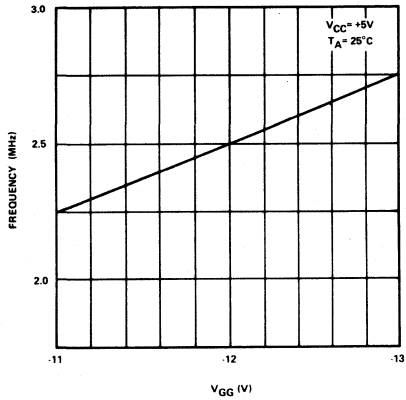
POWER SUPPLY CURRENT  
VERSUS POWER SUPPLY VOLTAGE



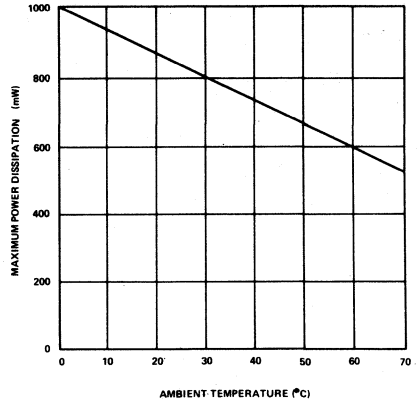
POWER SUPPLY CURRENT  
VERSUS TEMPERATURE



TYPICAL OPERATING FREQUENCY  
VERSUS SUPPLY VOLTAGE



PACKAGE MAXIMUM  
POWER DISSIPATION



### SILICON GATE MOS 2500 SERIES

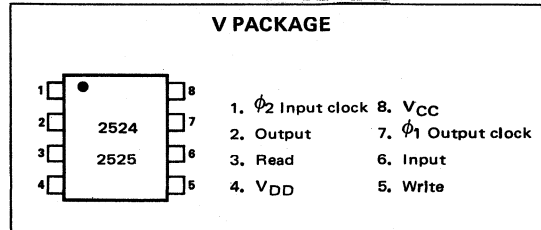
#### DESCRIPTION

These Signetics 2500 Series 512 and 1024 bit recirculating dynamic shift registers consist of enhancement mode P-channel MOS devices integrated on a single monolithic chip. Internal recirculation logic plus write and read controls are included on the chip.

#### SILICONE PACKAGING

Low cost silicone DIP packaging is implemented and reliability is assured by the use of Signetics unique silicon gate MOS process technology. Unlike the standard metal gate MOS process the silicon material over the gate oxide passivates the MOS transistors, and the deposited dielectric material over the silicon gate-oxide-substrate structure provides an ion barrier. In addition, Signetics proprietary surface passivation and silicone packaging techniques result in an MOS circuit with inherent high reliability and demonstrating superior moisture resistance, mechanical shock and ionic contamination barriers.

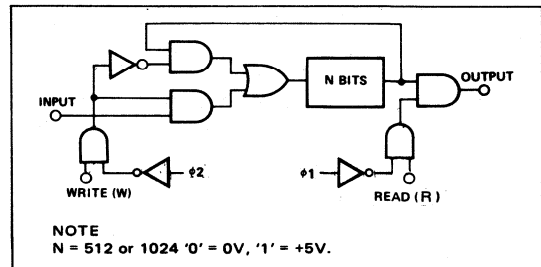
#### PIN CONFIGURATION (Top View)



#### FEATURES

- HIGH FREQUENCY OPERATION – 5MHz TYPICAL
- SINGLE 512, SINGLE 1024
- TTL, DTL COMPATIBLE
- WRITE AND READ CONTROLS INCLUDED
- LOW POWER DISSIPATION – 200 $\mu$ W/BIT AT 1 MHz
- +5, -5 POWER SUPPLIES
- STANDARD PACKAGE 8-LEAD DIP
- P-MOS SILICON GATE TECHNOLOGY

#### BLOCK DIAGRAM



#### APPLICATIONS

- FAST ACCESS SWAPPING MEMORY SYSTEMS
- LOW COST SEQUENTIAL ACCESS MEMORIES
- LOW COST BUFFER MEMORIES
- CRT REFRESH MEMORIES
- DELAY LINE MEMORY REPLACEMENT
- DRUM MEMORY REPLACEMENT

#### PROCESS TECHNOLOGY

Use of low threshold silicon gate technology allows high speed (5MHz typical) while reducing power dissipation and clock input capacitance dramatically as compared to other technologies. The use of low voltage circuitry minimizes power dissipation and facilitates interfacing with bipolar integrated circuits.

#### BIPOLAR COMPATIBILITY

The signal inputs of these registers can be driven directly by standard bipolar integrated (TTL, DTL, etc.) or by MOS circuits. The bare drain output stage provides driving capability for both MOS and bipolar integrated circuits (one standard TTL load).

#### TRUTH TABLE

WRITE	READ	FUNCTION
0	0	Recirculate, Output is '0'
0	1	Recirculate, Output is Data
1	0	Write Mode, Output is '0'
1	1	Read Mode Output is Data

#### PART IDENTIFICATION TABLE

PART NO.	BIT LENGTH	PACKAGE
2524V	512	8 pin DIP
2525V	1024	8 pin DIP

# SIGNETICS 512 AND 1024 BIT RECIRCULATING DYNAMIC SHIFT REGISTERS ■ 2524, 2525

## MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature (2)  $0^{\circ}\text{C}$  to  $+70^{\circ}\text{C}$   
 Storage Temperature  $-65^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$   
 Power Dissipation (2)  $535\text{mW}@T_A > 70^{\circ}\text{C}$   
 Data and Clock Input Voltages  
 and Supply Voltages with  
 respect to  $V_{CC}$   $+0.3\text{V}$  to  $-20\text{V}$

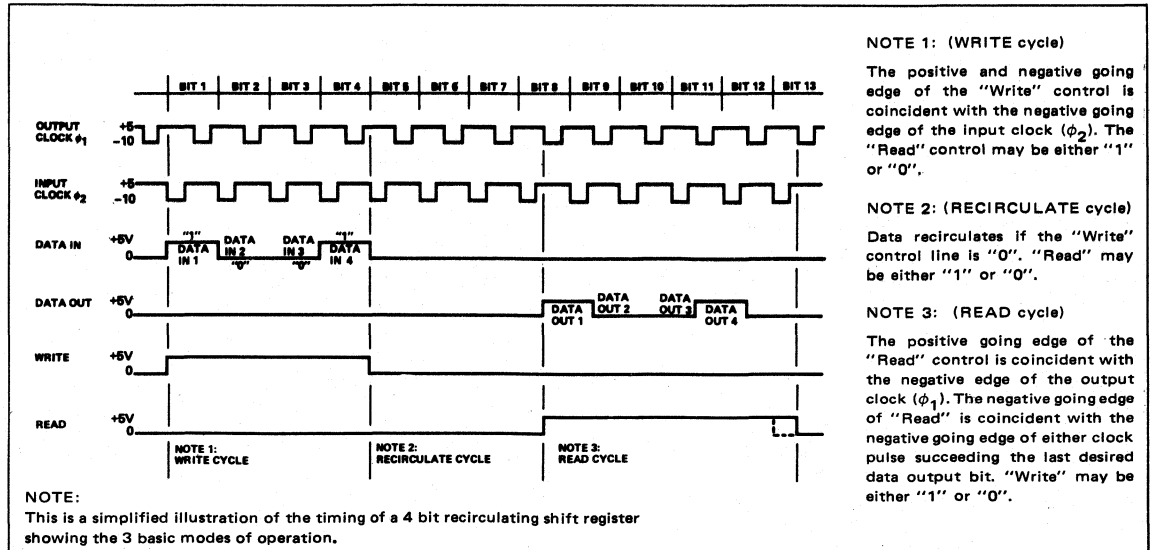
### NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a  $+150^{\circ}\text{C}$  maximum junction temperature and a thermal resistance of  $150^{\circ}\text{C}/\text{W}$  junction to ambient.
- All inputs are protected against static charge.
- See "Minimum Operating Frequency" graph for low limits on data rep. rate.
- All voltage measurements are referenced to ground.
- Manufacturer reserving the right to make design and process changes and improvements.
- Typical values are at  $+25^{\circ}\text{C}$  and nominal supply voltages.
- Parameters are valid over operating temperature range unless otherwise specified.
- Guaranteed input levels are stated for worst case conditions including a  $\pm 5\%$  variation in  $V_{CC}$  and a temperature variation of  $0^{\circ}\text{C}$  to  $+70^{\circ}\text{C}$ . Actual input requirements with respect to  $V_{CC}$  are  $V_{IH} = V_{CC} - 1.85\text{V}$  and  $V_{IL} = V_{CC} - 4.15\text{V}$ .
- $V_{OL}$  is a function of the input characteristics of the driven TTL/DTL gate  $I_{OI}$  and  $V_{CLAMP}$  and the value of the pull-down resistor ( $R_L$ ).

**DC CHARACTERISTICS**  $T_A = 0^{\circ}\text{C}$  to  $+70^{\circ}\text{C}$ ;  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{DD} = -5\text{V} \pm 5\%$  unless otherwise noted.

SYMBOL	TEST	MIN	TYPICAL	MAX	UNIT	CONDITION
$I_{LI}$	Input Load Current		10	500	nA	$V_{IN} = -5.5\text{V}; T_A = 25^{\circ}\text{C}$
$I_{LO}$	Output Leakage Current		10	1000	nA	$V_{\phi 1} = V_{\phi 2} = -12\text{V}; V_{DD} = -5\text{V}$ $V_{OUT} = -5.5\text{V}; T_A = 25^{\circ}\text{C}$
$I_{LC}$	Clock Leakage Current		10	1000	nA	$V_{ILC} = -12\text{V}; T_A = 25^{\circ}\text{C}$
$I_{DD}$	Power Supply Current: 2524		15	35	mA	Continuous Operation; $\phi_p W = 150\text{nS}; f = 1\text{ MHz}$
	2525		25	35	mA	$V_{ILC} = -12\text{V}; T_A = 25^{\circ}\text{C}$ $V_{DD} = -5.5\text{V}$
$V_{IL}$	Input "Low" Voltage	-5.0		+0.6	V	Note 9
$V_{IH}$	Input "High" Voltage	+3.4		5.3	V	Note 9
$V_{ILC}$	Clock Input "Low" Voltage	-12.0		-10.0	V	
$V_{IHC}$	Clock Input "High" Voltage	4.0		5.3	V	

## EXAMPLE TIMING DIAGRAM



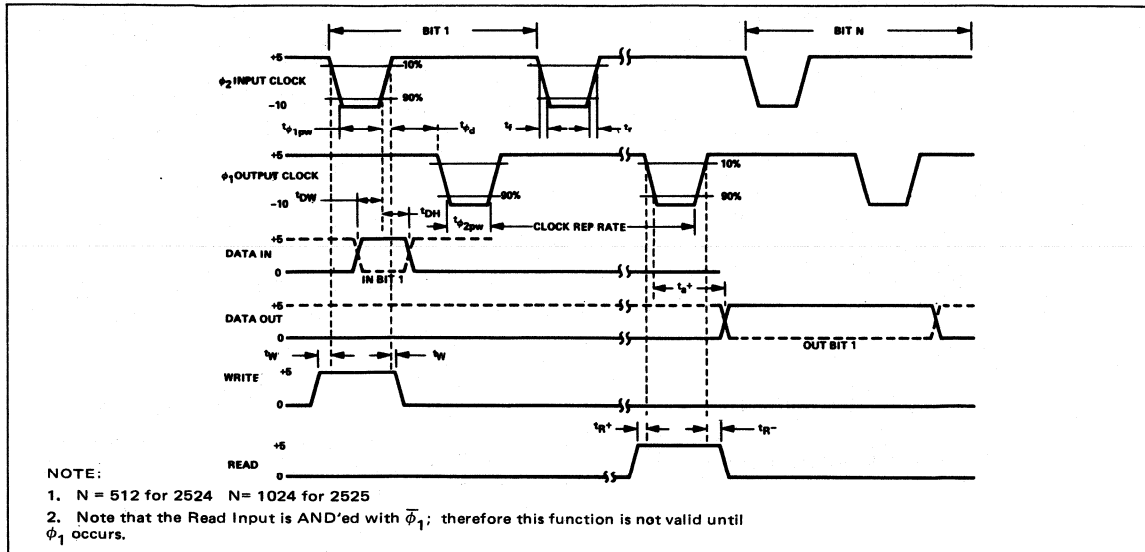


# SIGNETICS 512 AND 1024 BIT RECIRCULATING DYNAMIC SHIFT REGISTERS ■ 2524, 2525

## CONDITIONS OF TEST

Input rise and fall times: 10 sec Output load is 1 TTL gate

## TIMING DIAGRAM

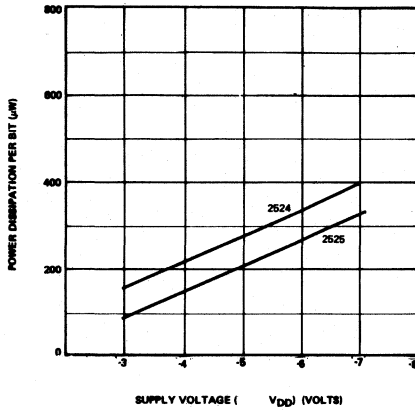


## AC CHARACTERISTICS $T_A = +25^\circ\text{C}$ $V_{CC} = +5V \pm 5\%$ ; $V_{DD} = -5V \pm 5\%$ ; $V_{ILC} = -11V$

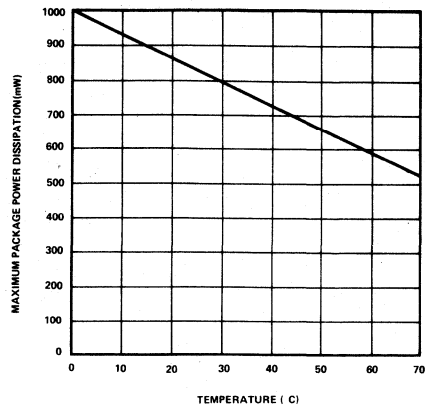
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
Frequency	Clock Data Rep Rate	.0005 (Note 4)	5	3	MHz	$W = R = V_{CC}$
$t_{\phi pw}$	Clock Pulse Width	135	85		ns	
$t_{\phi d}$	Clock Pulse Delay	10			ns	
$t_r, t_f$	Clock Pulse Transition	10		1000	ns	
$t_{DW}$	Data Write (Setup) Time	70			ns	
$t_{DH}$	Data to Clock Hold Time	20			ns	
$t_{a+}$	Clock to Data Out Delay			100	ns	
$t_{R-}$ $t_{W-}$	Clock to "Read" or "Write" Timing	0			ns	
$t_{R+}$ $t_{W+}$	Clock to "Read" or "Write" Timing	0			ns	
$C_{in}$	Input Capacitance			5	pF	1MHz; $V_I = V_{CC}$ ; $V_{AC} = 25m V_{p-p}$
$C_{out}$	Output Capacitance			5	pF	1MHz; $V_O = V_{CC}$ ; $V_{AC} = 25m V_{p-p}$
$C_{\phi}$	Clock Capacitance			80 160	pF pF	1MHz; $V = V_{CC}$ ; $V_{AC} = 25m V_{p-p}$
$V_{OL}$	Output "Low" Voltage		-1.0		V	$R_L = 3.0K$ ; 1 TTL Load ( $I_L = 1.6mA$ ) Note 10
$V_{OH1}$	Output "High" Voltage Driving 1 TTL Load	2.4	3.5		V	$R_L = 3.0K$ ; 1 TTL Load ( $I_L = 100\mu A$ )
$V_{OH2}$	Output "High" Voltage Driving MOS	3.6	4.0		V	$R_L = 5.6K$ ; $C_L = 10pF$

CHARACTERISTIC CURVES

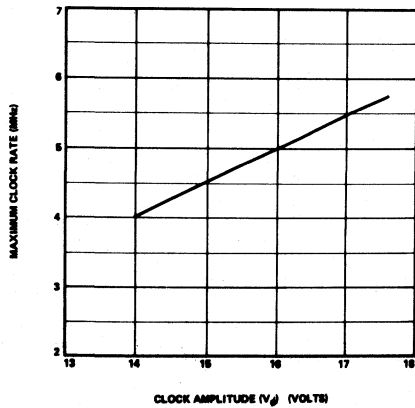
POWER DISSIPATION/BIT  
VERSUS SUPPLY VOLTAGE



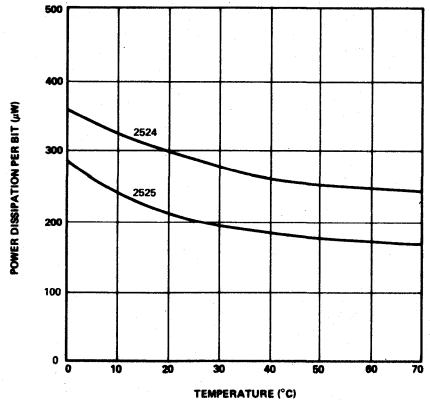
MAXIMUM PACKAGE POWER  
DISSIPATION VERSUS TEMPERATURE



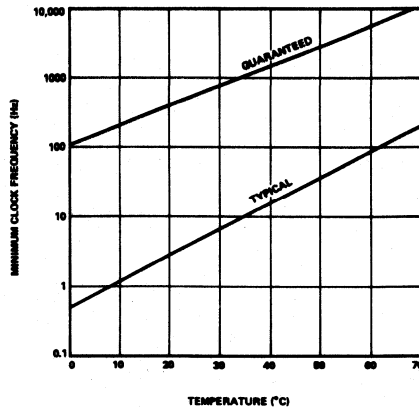
MAXIMUM CLOCK RATE  
VERSUS CLOCK AMPLITUDE



POWER DISSIPATION/BIT  
VERSUS TEMPERATURE



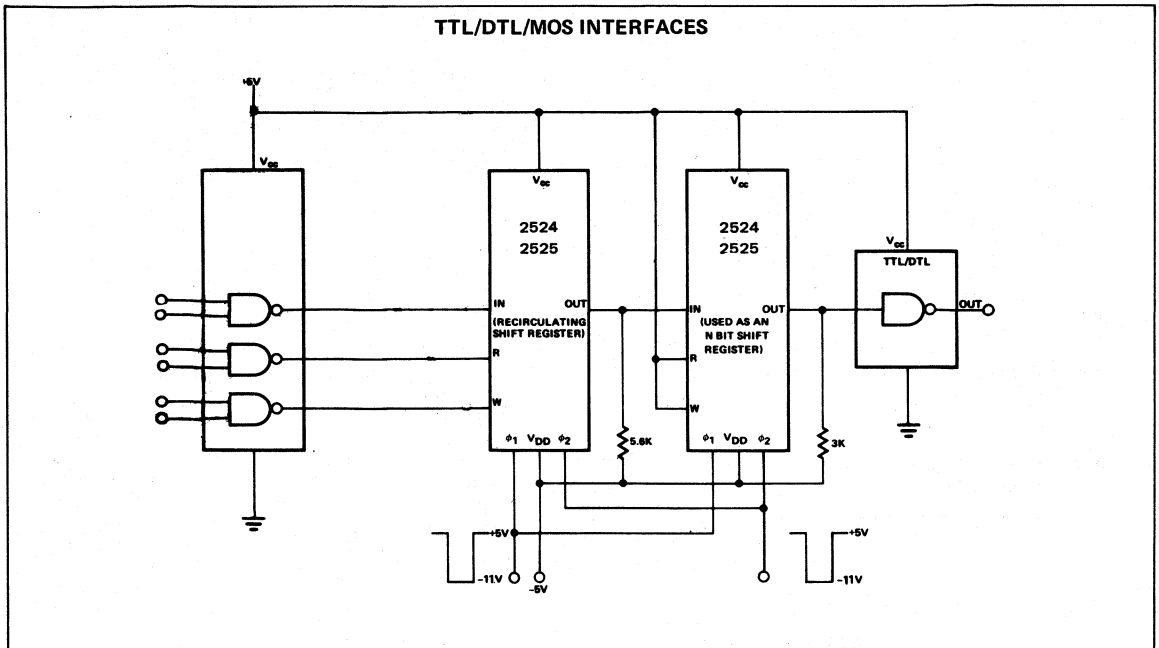
MINIMUM OPERATING CLOCK  
FREQUENCY VERSUS TEMPERATURE



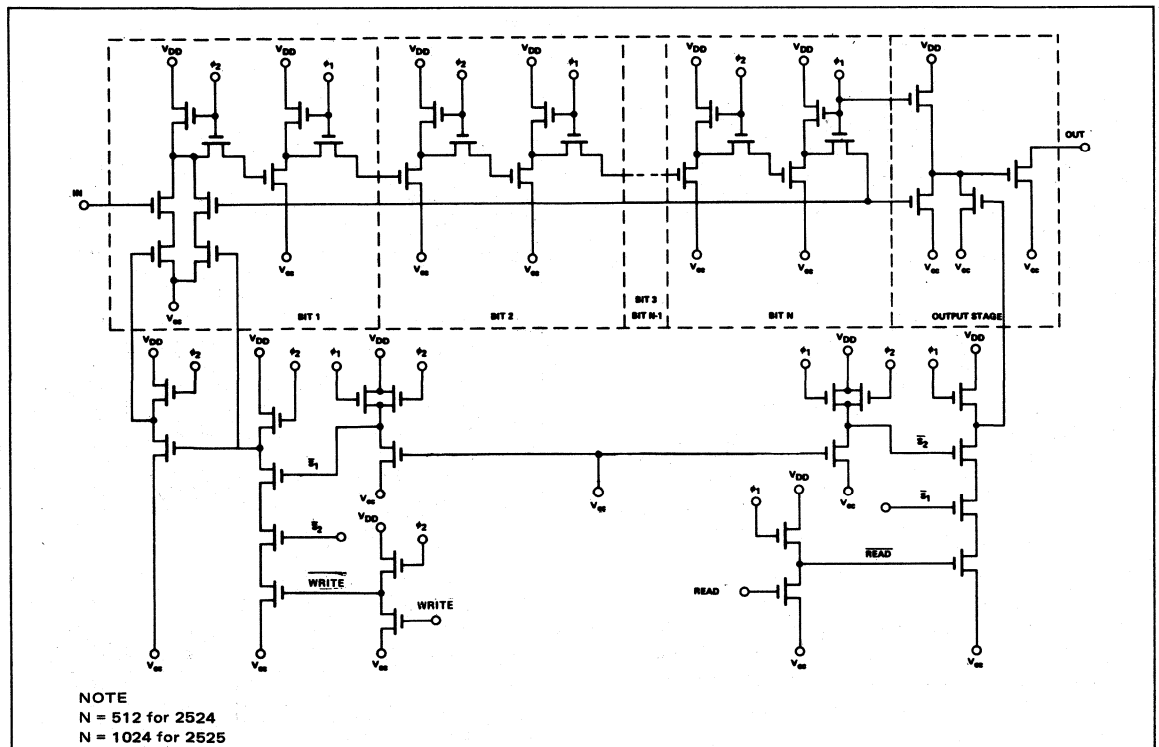
NOTE:

Conditions for typical curves: V<sub>CC</sub> = +5V, V<sub>DD</sub> = -5V, clock duty cycle = 35%, f<sub>CLK</sub> = 3MHz, V<sub>φp-p</sub> = 16V, φ<sub>PW1</sub> = φ<sub>PW2</sub> = 80ns, T<sub>A</sub> = +25°C unless otherwise noted.

APPLICATIONS DATA



CIRCUIT SCHEMATIC



SILICON GATE MOS 2500 SERIES

### DESCRIPTION

The 2526 is a high speed 5,184-bit Static Read-Only Memory. It may be organized as 64x9x9 for use as a character generator, or as a 512x9 ROM for general purpose use. This device has TTL compatible inputs and outputs and requires +5V and -12V power supplies. A  $\overline{\text{READ}}$  input controls the entry of data from the ROM into output latches. Three-state outputs allow OR tying for implementing larger memories. OUTPUT ENABLE controls the nine output devices without affecting address circuitry.

### FEATURES

- 64x9x9 ORGANIZATION
- 512x9 ORGANIZATION
- 625ns TYPICAL ACCESS TIME
- STATIC OPERATION
- OUTPUT LATCHES
- TTL/DTL COMPATIBLE INPUTS
- TTL/DTL COMPATIBLE TRI-STATE OUTPUTS
- $V_{CC} = +5V, V_{GG} = -12V$
- 24-PIN SILICONE DIP
- P-MOS SILICON GATE TECHNOLOGY

### APPLICATIONS

VERTICAL OR RASTER SCAN DISPLAYS (7x9 MATRIX)  
 PRINTER CHARACTER GENERATOR  
 PANEL DISPLAYS AND BILLBOARDS  
 MICRO-PROGRAMMING  
 CODE CONVERSION  
 PROGRAM STORAGE

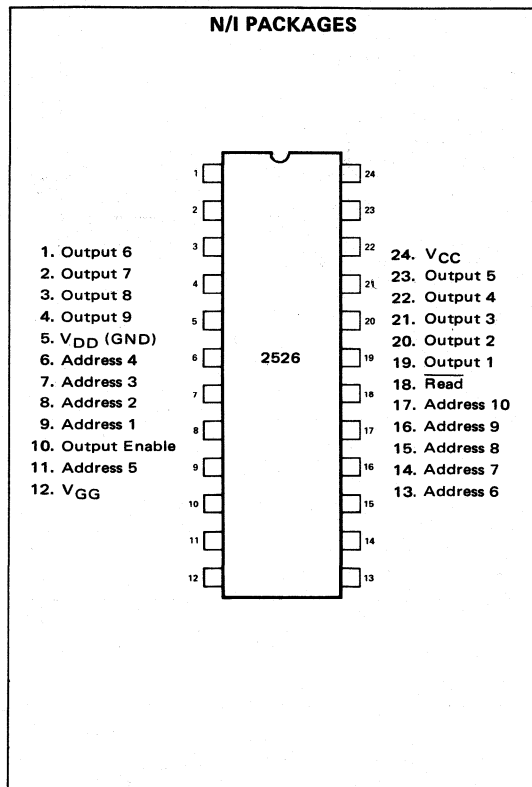
### BIPOLAR COMPATIBILITY

All inputs of the 2526 can be driven directly by standard bipolar integrated circuits (TTL, DTL, etc.). The data output buffers are capable of sinking a minimum of 1.6mA to drive one standard TTL load.

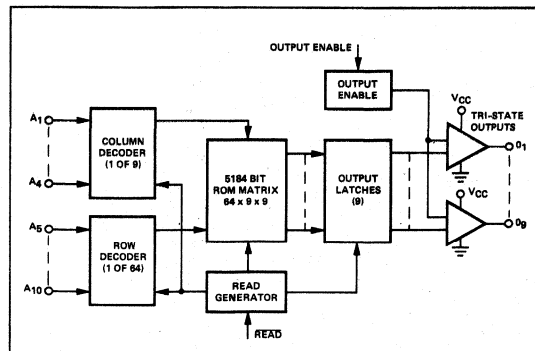
### STANDARD CODES

The 2526 is available with ASCII-addressed characters using a 7x9 dot matrix. The two remaining locations in the 9x9 matrix are used for BCDIC-to-ASCII and BAUDOT-to-ASCII code conversions. The 2526/CM3940 is organized for raster scan and the 2526/CM3400 is for vertical scan.

### PIN CONFIGURATION (Top View)



### BLOCK DIAGRAM



### PART IDENTIFICATION

PART	OP. TEMP. RANGE	PACKAGE
2526N	0-70°C	24-Pin Silicone DIP
2526I	0-70°C	24-Pin Ceramic DIP

**MAXIMUM GUARANTEED RATINGS (1)**

Operating Ambient Temperature 0°C to 70°C  
Storage Temperature -65°C to +150°C

Package Power Dissipation<sup>2</sup> @ 70°C

Input<sup>3</sup> and Supply Voltages  
with respect to V<sub>CC</sub>

730mW

+0.3 to -20V

**DC CHARACTERISTICS**

T<sub>A</sub> = 0°C to +70°C, V<sub>CC</sub> = +5V ±5%; V<sub>GG</sub> = -12V ±5%; unless otherwise noted. (See notes 4, 5, 6, 7)

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current		10	500	nA	V <sub>IN</sub> = -5.5V T <sub>A</sub> = 25°C
I <sub>LO</sub>	Output Leakage Current		10	1000	nA	V <sub>OUT</sub> = 0V T <sub>A</sub> = 25°C V <sub>CE</sub> = V <sub>CC</sub>
I <sub>CC</sub>	V <sub>CC</sub> Power Supply Current		30	45	mA	(8)
I <sub>GG</sub>	V <sub>GG</sub> Power Supply Current		30	45	mA	(8)
V <sub>IL</sub>	Input Logic "0"	-5		+0.6	V	(13)
V <sub>IH</sub>	Input Logic "1"	+3.4		5.3	V	(13)

**AC CHARACTERISTICS**

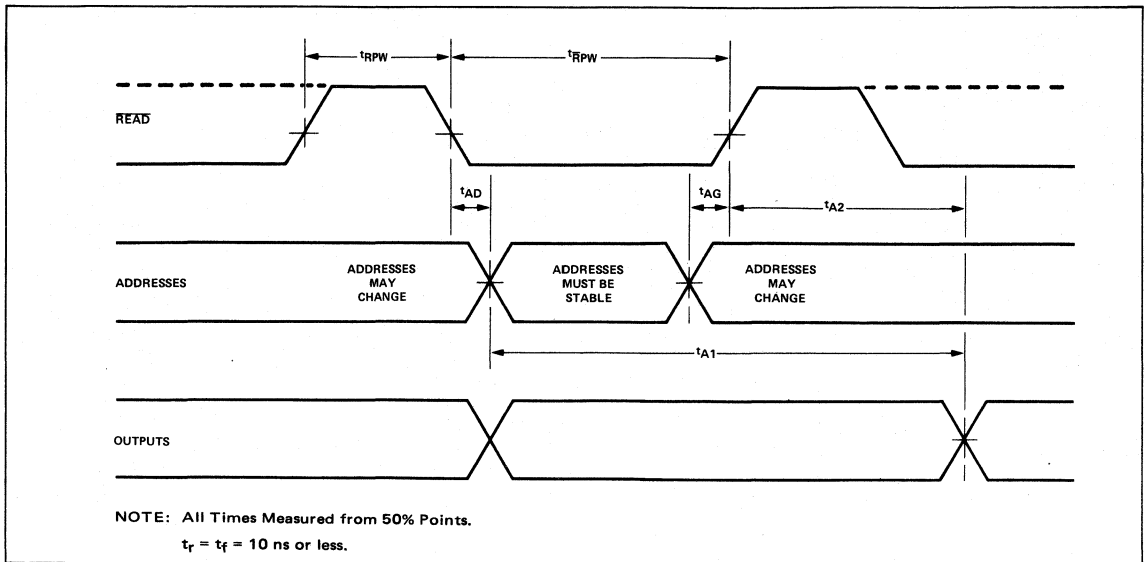
T<sub>A</sub> = 0°C to +70°C, V<sub>CC</sub> = 5V ±5%; V<sub>GG</sub> = -12V ±5%; unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
V <sub>OL</sub>	Output Logic "zero"			+5	V	I <sub>OL</sub> = 1.6mA
V <sub>OH</sub>	Output Logic "one"	+3.8			V	I <sub>OH</sub> = 100μA
t <sub>RPW11</sub>	Read Pulse Width	250	200		ns	
t <sub>RPW10</sub>	Read Pulse Width	500	400		ns	
t <sub>AD</sub>	Address Delay Time (12)			50	ns	
t <sub>AG</sub>	Address-Read Pulse Gap (12)			50	ns	
t <sub>A1</sub>	Address to Output Delay		625	700	ns	(9)
t <sub>A2</sub>	End of Read Pulse to Output Delay		200	250	ns	(9)
C <sub>IN</sub>	Address Input Capacitance			10	pF	f = 1MHz,
t <sub>OE</sub>	Output Enable to Output Delay		100	250	ns	V <sub>AC</sub> = 25mV p-p V <sub>IN</sub> = V <sub>CC</sub>

**NOTES:**

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 110°C/W junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and nominal supply voltages.
- Outputs Open, t<sub>RPW</sub> = 250ns, t<sub>RPW</sub> = 500ns.
- t<sub>A</sub> = 0°C to +70°C
- During t<sub>RPW1</sub> data is clocked into the output latches and the address decoders are precharged in preparation for the next cycle.
- During t<sub>RPW1</sub> addresses are decoded and sent to the memory matrix; and the stored memory data is moved to the data inputs of the output RS latches. This data is clocked into the output latches at the end (rising edge) of the READ pulse. After t<sub>A2</sub> data appears at the output terminals.
- Addresses must be stable within 50ns after the READ line falls and must remain stable until at least 50ns before the READ line goes high.
- Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.

**TIMING DIAGRAM**

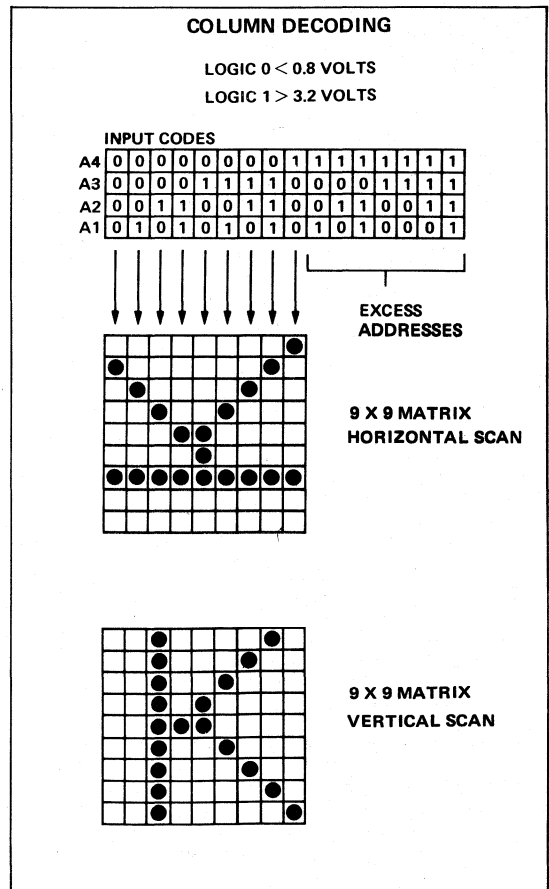


**APPLICATION INFORMATION**

The 2526 is organized to provide 64 character locations with each character described by a 9x9 matrix of bits. The six address inputs A5 through A10 are decoded directly to provide a 1-of-64 character selection. The four address inputs A1 through A4 are decoded to provide a 1-of-9 selection of scans within each character. Since four address lines can generate 16 scan selections instead of only 9, there are seven excess codes. The 1-of-9 scan decoder forces the excess input codes to generate all logic "0s" at the output latches.

The 9x9 dot configuration for each character allows the 2526 to be used as a 7x9 character generator with either vertical or horizontal scanning techniques. In the horizontal case, as each slice through the character is extracted from the ROM, the two extra bits may be ignored and the seven remaining bits used to control the dot formations. In the vertical case, each slice through the character provides the full nine bits needed to control the dots. Two complete scans are not used for dots and may be ignored or may be used for code translations.

For use as a 512x9 ROM, simply tie address A4 to a logical zero thus eliminating the excess input addresses. The other nine address lines can then be used to address 512 contiguous locations in the memory.



STANDARD CHARACTER FONT

CM 3400

ASCII SET, VERTICAL SCAN 7X9 WITH CODE CONVERSION

COLUMN ADDRESSES							
A1	0	1	0	1	0	1	0
A2	0	0	1	1	0	0	1
A3	0	0	0	1	1	1	1
A4	0	0	0	0	0	0	1

DECIMAL ADDRESS "0" (A <sub>8</sub> -A <sub>1</sub> )	DECIMAL ADDRESS "1"	DECIMAL ADDRESS "2"	DECIMAL ADDRESS "3"	DECIMAL ADDRESS "4"	DECIMAL ADDRESS "5"	DECIMAL ADDRESS "6"	DECIMAL ADDRESS "7"	DECIMAL ADDRESS "8"
DECIMAL ADDRESS "9"	DECIMAL ADDRESS "9"	DECIMAL ADDRESS "10"	DECIMAL ADDRESS "11"	DECIMAL ADDRESS "12"	DECIMAL ADDRESS "13"	DECIMAL ADDRESS "14"	DECIMAL ADDRESS "15"	DECIMAL ADDRESS "16"
DECIMAL ADDRESS "16"	DECIMAL ADDRESS "17"	DECIMAL ADDRESS "18"	DECIMAL ADDRESS "19"	DECIMAL ADDRESS "20"	DECIMAL ADDRESS "21"	DECIMAL ADDRESS "22"	DECIMAL ADDRESS "23"	DECIMAL ADDRESS "24"
DECIMAL ADDRESS "24"	DECIMAL ADDRESS "25"	DECIMAL ADDRESS "26"	DECIMAL ADDRESS "27"	DECIMAL ADDRESS "28"	DECIMAL ADDRESS "29"	DECIMAL ADDRESS "30"	DECIMAL ADDRESS "31"	DECIMAL ADDRESS "32"
DECIMAL ADDRESS "32"	DECIMAL ADDRESS "33"	DECIMAL ADDRESS "34"	DECIMAL ADDRESS "35"	DECIMAL ADDRESS "36"	DECIMAL ADDRESS "37"	DECIMAL ADDRESS "38"	DECIMAL ADDRESS "39"	DECIMAL ADDRESS "40"
DECIMAL ADDRESS "40"	DECIMAL ADDRESS "41"	DECIMAL ADDRESS "42"	DECIMAL ADDRESS "43"	DECIMAL ADDRESS "44"	DECIMAL ADDRESS "45"	DECIMAL ADDRESS "46"	DECIMAL ADDRESS "47"	DECIMAL ADDRESS "48"
DECIMAL ADDRESS "48"	DECIMAL ADDRESS "49"	DECIMAL ADDRESS "50"	DECIMAL ADDRESS "51"	DECIMAL ADDRESS "52"	DECIMAL ADDRESS "53"	DECIMAL ADDRESS "54"	DECIMAL ADDRESS "55"	DECIMAL ADDRESS "56"
DECIMAL ADDRESS "54"	DECIMAL ADDRESS "57"	DECIMAL ADDRESS "58"	DECIMAL ADDRESS "59"	DECIMAL ADDRESS "60"	DECIMAL ADDRESS "61"	DECIMAL ADDRESS "62"	DECIMAL ADDRESS "63"	DECIMAL ADDRESS "64"

NOTES

1. BCDIC to ASCII in leftmost column, Baudot to ASCII in next column to right.
2. Undefined addresses result in all outputs going low (TTL "0").
3. Black squares in character font are high (TTL "1").

STANDARD CHARACTER FONT

CM 3940

ASCII SET, RASTER SCAN 7X9 WITH CODE CONVERSION

ROM ADDRESS	OUTPUTS
A <sub>1</sub> A <sub>2</sub> A <sub>3</sub> A <sub>4</sub>	O <sub>0</sub> O <sub>1</sub> O <sub>2</sub> O <sub>3</sub> O <sub>4</sub> O <sub>5</sub> O <sub>6</sub> O <sub>7</sub> O <sub>8</sub>

0	0	0	0
0	0	0	1
0	0	1	0
0	1	1	1
0	1	0	0
0	1	0	1
0	1	1	0
0	1	1	1
1	0	0	0

DECIMAL ADDRESS "0" (A <sub>5</sub> -A <sub>10</sub> )	DECIMAL ADDRESS "1"	DECIMAL ADDRESS "2"	DECIMAL ADDRESS "3"	DECIMAL ADDRESS "4"	DECIMAL ADDRESS "5"	DECIMAL ADDRESS "6"	DECIMAL ADDRESS "7"
DECIMAL ADDRESS "8"	DECIMAL ADDRESS "9"	DECIMAL ADDRESS "10"	DECIMAL ADDRESS "11"	DECIMAL ADDRESS "12"	DECIMAL ADDRESS "13"	DECIMAL ADDRESS "14"	DECIMAL ADDRESS "15"
DECIMAL ADDRESS "16"	DECIMAL ADDRESS "17"	DECIMAL ADDRESS "18"	DECIMAL ADDRESS "19"	DECIMAL ADDRESS "20"	DECIMAL ADDRESS "21"	DECIMAL ADDRESS "22"	DECIMAL ADDRESS "23"
DECIMAL ADDRESS "24"	DECIMAL ADDRESS "25"	DECIMAL ADDRESS "26"	DECIMAL ADDRESS "27"	DECIMAL ADDRESS "28"	DECIMAL ADDRESS "29"	DECIMAL ADDRESS "30"	DECIMAL ADDRESS "31"
DECIMAL ADDRESS "32"	DECIMAL ADDRESS "33"	DECIMAL ADDRESS "34"	DECIMAL ADDRESS "35"	DECIMAL ADDRESS "36"	DECIMAL ADDRESS "37"	DECIMAL ADDRESS "38"	DECIMAL ADDRESS "39"
DECIMAL ADDRESS "40"	DECIMAL ADDRESS "41"	DECIMAL ADDRESS "42"	DECIMAL ADDRESS "43"	DECIMAL ADDRESS "44"	DECIMAL ADDRESS "45"	DECIMAL ADDRESS "46"	DECIMAL ADDRESS "47"
DECIMAL ADDRESS "48"	DECIMAL ADDRESS "49"	DECIMAL ADDRESS "50"	DECIMAL ADDRESS "51"	DECIMAL ADDRESS "52"	DECIMAL ADDRESS "53"	DECIMAL ADDRESS "54"	DECIMAL ADDRESS "55"
DECIMAL ADDRESS "56"	DECIMAL ADDRESS "57"	DECIMAL ADDRESS "58"	DECIMAL ADDRESS "59"	DECIMAL ADDRESS "60"	DECIMAL ADDRESS "61"	DECIMAL ADDRESS "62"	DECIMAL ADDRESS "63"

NOTES

1. BCDIC to ASCII in leftmost column, Baudot to ASCII in next column to right.
2. Undefined addresses result in all outputs going low (TTL "0").
3. Black squares in character font are high (TTL "1").



2526 CUSTOM CODING  
INFORMATION

## PUNCHED CARD INPUT

## Comment/I.D. Cards:

Card No.	Column	Information
1	1	"C"
	2	Blank
	3-17	"SIGNETICS 2526N/CM"
	18-26	Blank
	27-71	Customer I'D' (Company, Project, Part No., etc.)
72	Blank	
	73-80	Date
2	1	"C"
	2	Blank
	3-80	Person responsible for reviewing Signetics truth table.
3	1	"C"
	2	Blank
	3-80	Customer Street Address
4	1	"C"
	2	Blank
	3-80	Customer City, State, Zip.
5	1	"C"
	2	Blank
	3-80	Name

## Data Cards (Continued)

Card No.	Column	Information	
1 (Cont'd)	30	Blank	
	31-39	Fourth column	
	40	Blank	
	41-49	Fifth column	
	50	Blank	
	51-59	Sixth column	
	60	Blank	
	61-69	Seventh column	
	70-71	Blank	
	72	Data card number of first character, ("1").	
	73	Blank	
	74-76	Anything – customer option.	
	77	Blank	
	78-80	Decimal character number, ("000")	
	2	1-9	Eighth column
10		Blank	
11-19		Ninth column	
20-70		Anything – customer option.	
71		Blank	
72		Data card number of first character, ("2").	
73		Blank	
74-76		Customer option	
77		Blank	
78-80		Decimal character number, ("000").	
3		1-9	First column, second character, (Etc., as Card 1)
			Second character is "001".
4	(Etc., as Card 2)		
128	78-80	Decimal character number, ("063").	

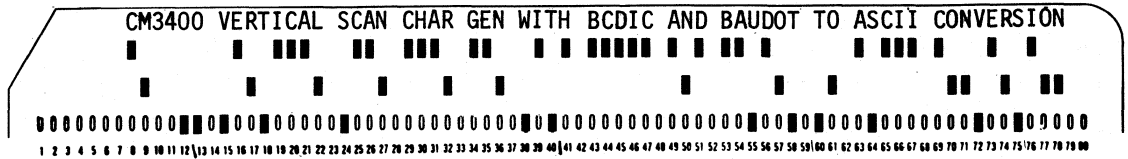
## Data Cards

Card No.	Column	Information
1	1-9	Binary outputs of rows 9 through 1, (MSB at 9), first column, first character, (first character is "000"). Logic "1" is high output (3.2V, min.).
	10	Blank
	11-19	Binary outputs of second column, first character.
	20	Blank
	21-29	Third column

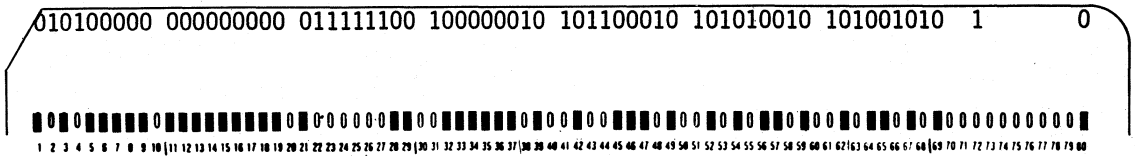
**SIGNETICS 64 X 9 X 9 ROM STATIC CHARACTER GENERATOR ■ 2526**

**EXAMPLES:**

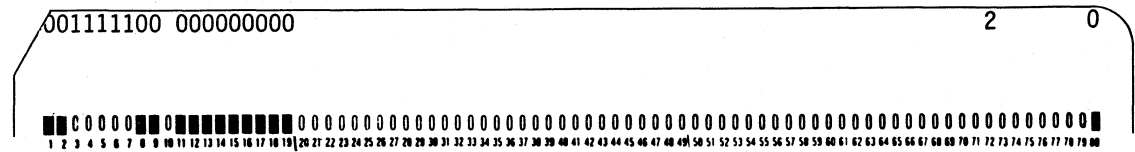
**I.D. Card**



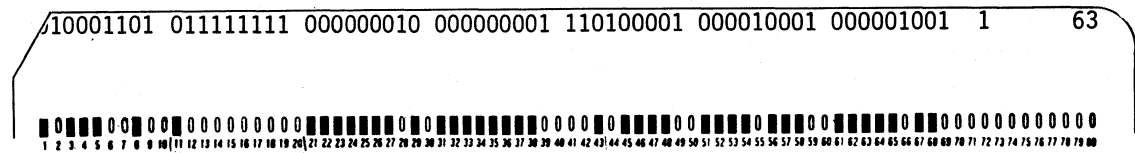
**First Data Card – First Character**



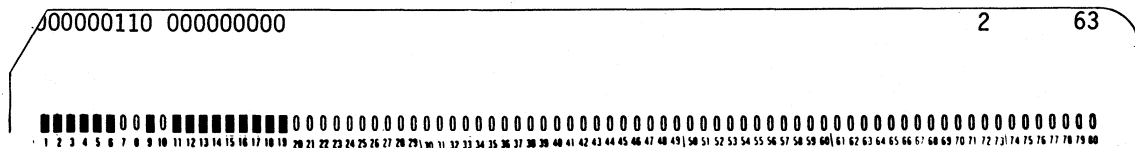
**Second Data Card – First Character**



**First Data Card – Last Character**



**Second Data Card – Last Character**



**TRUTH TABLE INPUT:** A truth table may be submitted at a greater non-recurring cost to the customer. A format similar to the one shown below is satisfactory.

ADDRESS										DECIMAL ADDRESS	OUTPUT DATA								CHARACTER		
A <sub>10</sub>	A <sub>9</sub>	A <sub>8</sub>	A <sub>7</sub>	A <sub>6</sub>	A <sub>5</sub>	A <sub>4</sub>	A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>		O <sub>9</sub>	O <sub>8</sub>	O <sub>7</sub>	O <sub>6</sub>	O <sub>5</sub>	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>		
0	0	0	0	0	0	0	0	0	0	000											↑ FIRST CHARACTER ↓
0	0	0	0	0	0	0	0	0	1	001											
0	0	0	0	0	0	0	0	1	0	002											
0	0	0	0	0	0	0	0	1	1	003											
0	0	0	0	0	0	0	1	0	0	004											
0	0	0	0	0	0	0	1	0	1	005											
0	0	0	0	0	0	0	1	1	0	006											
0	0	0	0	0	0	1	0	0	0	007											
0	0	0	0	0	0	1	0	0	0	008											↑ SECOND CHARACTER ↓
0	0	0	0	0	1	0	0	0	0	016											
0	0	0	0	0	1	0	0	0	1	017											
										Etc.											

### SILICON GATE 2500 SERIES

#### DESCRIPTION

The Signetics 2500 Dual 256, bit recirculating static shift register consist of enhancement mode P-channel silicon gate MOS devices integrated on a single monolithic chip.

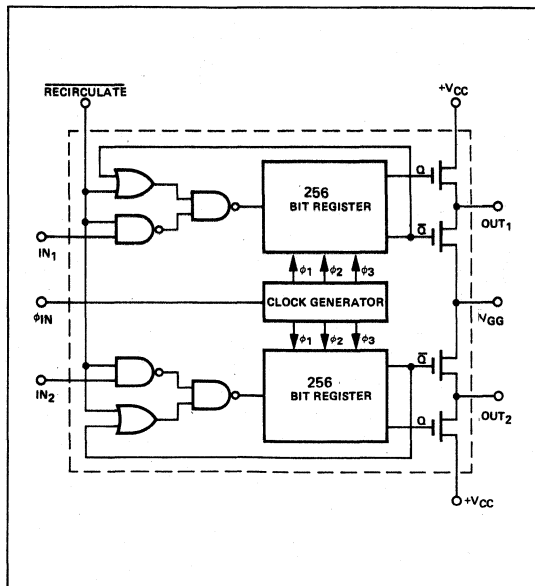
#### FEATURES

- PUSH-PULL OUTPUTS
- TTL/DTL COMPATIBLE CLOCK
- LOW CLOCK CAPACITANCE
- RECIRCULATION PATH ON CHIP
- THREE BIT LENGTHS AVAILABLE
- HIGH FREQUENCY OPERATION – 2.5 MHz TYPICAL
- TTL, DTL COMPATIBLE INPUTS AND OUTPUTS
- STANDARD PACKAGE – 8 LEAD SILICONE DIP
- P-MOS SILICON GATE TECHNOLOGY

#### APPLICATIONS

LOW COST SEQUENTIAL ACCESS MEMORIES  
 LOW COST STATIC BUFFER MEMORIES  
 CRT REFRESH MEMORIES – LINE STORAGE  
 DELAY LINES

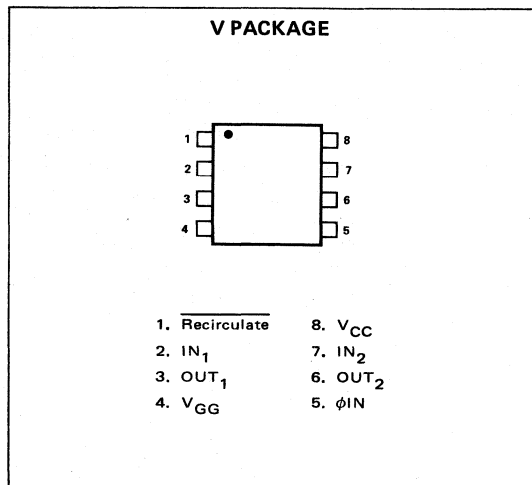
#### BLOCK DIAGRAM



#### BIPOLAR COMPATIBILITY

The clock and signal inputs of these registers can be driven directly by standard bipolar integrated (TTL, DTL, etc.) or by MOS circuits. The outputs drive directly into TTL/DTL without requiring external resistors.

#### PIN CONFIGURATION (Top View)



#### TRUTH TABLE

RECIRCULATE	INPUT	FUNCTION
0	0	Recirculate
0	1	Recirculate
1	0	"0" is Written
1	1	"1" is Written

NOTE: "0" = 0V; "1" = +5V

#### MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature (2) 0°C to +70°C

Storage Temperature -65°C to +150°C

Package Power Dissipation  
 at T<sub>A</sub> = 70°C 535 mW

Data and Clock Input Voltages  
 and Supply Voltages with  
 respect to V<sub>CC</sub> +0.3V to -20V

# SIGNETICS DUAL 256-BIT STATIC SHIFT REGISTER ■ 2527

## NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 150°C/W junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and nominal supply voltages.
- Guaranteed input levels are stated for worst case conditions including a ±5% variation in  $V_{CC}$  and a temperature variation of 0°C to +70°C. Actual input requirements with respect to  $V_{CC}$  are  $V_{IH} = V_{CC} - 1.85V$  and  $V_{IL} = V_{CC} - 4.15V$ .

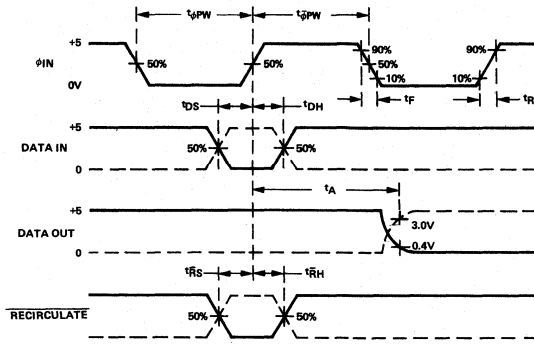
DC CHARACTERISTICS  $T_A = 0^\circ C$  to  $+70^\circ C$ ;  $V_{CC} = +5V \pm 5\%$ ;  $V_{GG} = -12V \pm 5\%$  unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$I_{LI}$	Input Load Current		10	500	nA	$V_{IN} = 5.5V, T_A = 25^\circ C$
$I_{LC}$	Clock Leakage Current		10	500	nA	$V_{ILC} = 0V, T_A = 25^\circ C$
$I_{GG}$	Power Supply Current		28	35	mA	Continuous Operation $F = 1.5 MHz, T_A = 25^\circ C$ Outputs Open
$V_{IL}$	Input "Low" Voltage			+0.6	V	(8)
$V_{IH}$	Input "High" Voltage	+3.4		5.3	V	(8)
$V_{ILC}$	Clock Input "Low" Voltage			+0.6	V	(8)
$V_{IHC}$	Clock Input "High" Voltage	+3.4		5.3	V	(8)

AC CHARACTERISTICS  $T_A = 0^\circ C$  to  $+70^\circ C$ ,  $V_{CC} = +5V \pm 5\%$ ;  $V_{GG} = -12V \pm 5\%$ ,

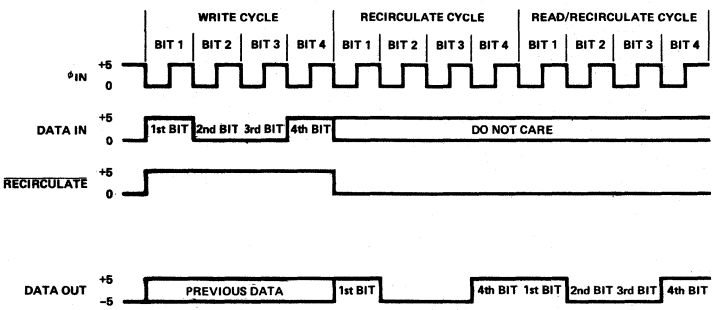
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
FREQUENCY	Clock Rep Rate	DC	2.5	1.5	MHz	See Maximum Frequency Curve
$t_{\phi PW}$	Clock Pulse Width	0.2	0.1	100	$\mu s$	See Timing Diagram Note
$\overline{t_{\phi PW}}$	Clock Pulse Width	0.2		DC	$\mu s$	
$t_R t_F$	Clock Pulse Transition			1	$\mu s$	
$t_{DS}$	Data Set-up Time	50			ns	
$t_{DH}$	Data Hold Time	50			ns	
$t_A$	Clock to Data Out Delay		330	450	ns	$I_{OL} = 1.6mA$
$t_{RS}$	Recirculate Set-up Time	50			ns	
$t_{RH}$	Recirculate Hold Time	50			ns	
$C_{IN}$	Input Capacitance			5	pF	@ 1 MHz; $V_{IN} = V_{CC}$ ; $V_{AC} = 25mV$ p-p
$C_\phi$	Clock Capacitance			5	pF	@ 1 MHz; $V_\phi = V_{CC}$ ; $V_{AC} = 25mV$ p-p
$V_{OL}$	Output "Low" Voltage			+0.5	V	$I_{OL} = 1.6mA$
$V_{OH}$	Output "High" Voltage	+3.8			V	$I_{OH} = 100\mu A$

**TIMING DIAGRAM**



$t_R = t_F < 10$  NSEC FOR ALL INPUTS

**NOTE: FOR STATIC OPERATION, THE INPUT CLOCK MUST BE STOPPED IN THE TTL "1" STATE IN ORDER TO RETAIN DATA (SEE CLOCK PULSE WIDTH SPECIFICATION).**

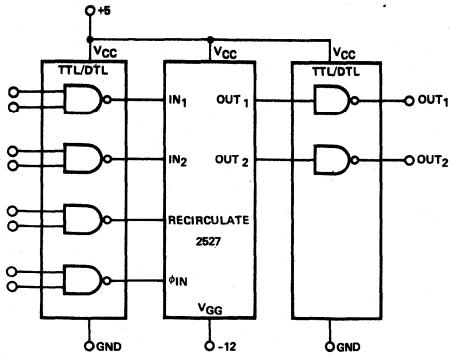


**WRITE CYCLE**  
 THE POSITIVE-GOING EDGE OF THE RECIRCULATE CONTROL IS COINCIDENT WITH THE NEGATIVE-GOING CLOCK EDGE. THE OUTPUT ENABLE CONTROL MAY BE EITHER "1" OR "0". IF IT IS "1", PREVIOUS DATA WILL BE READ, AND THE 1st BIT WILL BE READ AFTER THE FOURTH RISING CLOCK EDGE.

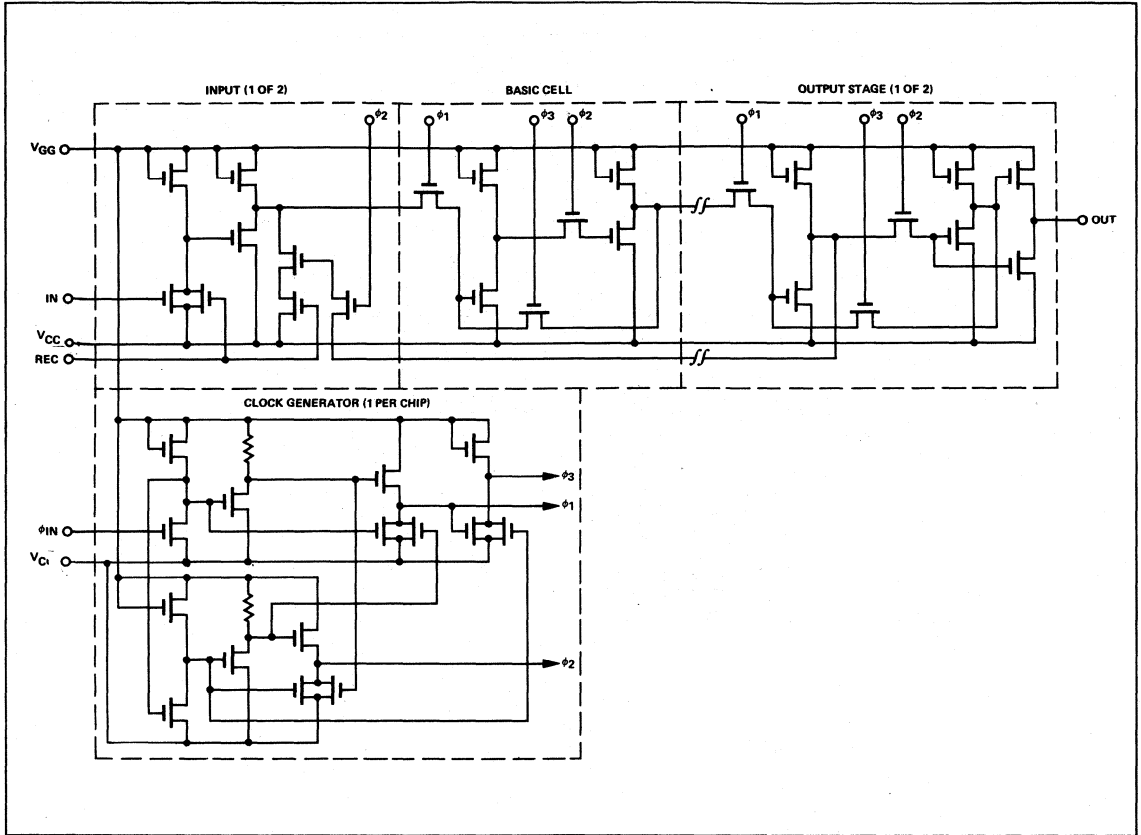
**RECIRCULATE CYCLE**  
 DATA RECIRCULATES WHILE THE RECIRCULATE CONTROL IS "0". NEW INPUT DATA IS IGNORED. OUTPUT DATA IS READ OUT DURING THIS TIME.

**APPLICATIONS INFORMATION**

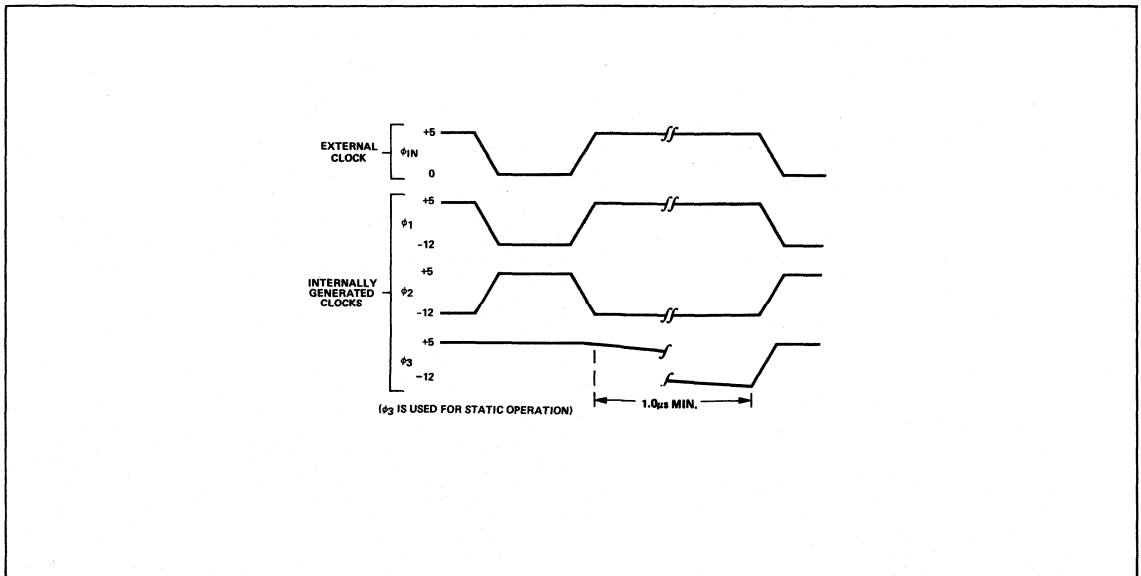
**TTL/DTL/MOS INTERFACES**



SCHEMATIC DIAGRAM

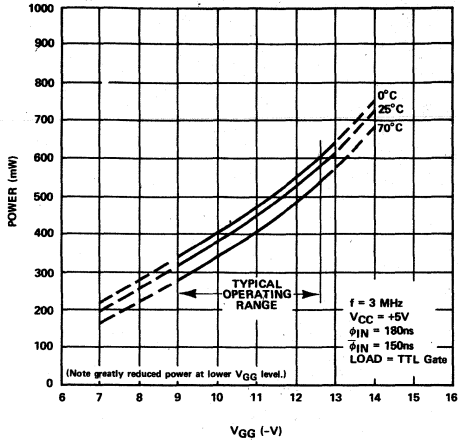


CLOCKING WAVEFORMS

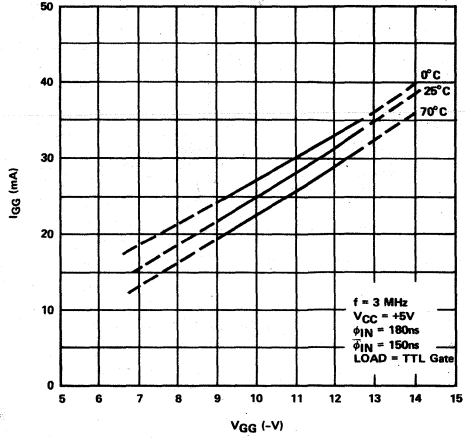


TYPICAL CHARACTERISTIC CURVES

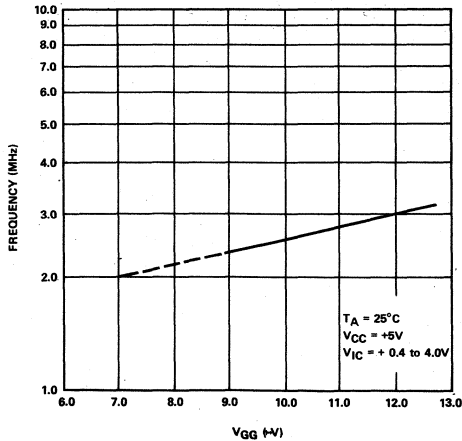
POWER DISSIPATION VS SUPPLY VOLTAGE



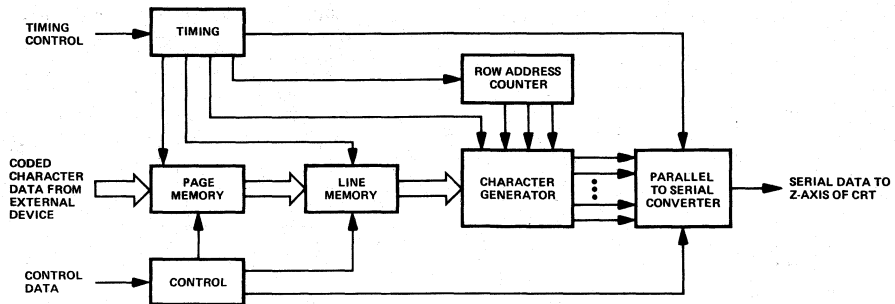
SUPPLY CURRENT VS SUPPLY VOLTAGE



TYPICAL DATA RATE VS SUPPLY VOLTAGE



APPLICATIONS INFORMATION (Cont'd)



**PAGE MEMORY:** THIS MEMORY CONTAINS CHARACTER CODES. TYPICALLY, IT CONTAINS THE SAME NUMBER OF CHARACTER CODES AS THE NUMBER OF CHARACTER ON A FULL SCREEN.

**LINE MEMORY:** THIS MEMORY CONTAINS THE CHARACTER CODES FOR ONE LINE OF THE CRT DISPLAY.

**CHARACTER GENERATOR:** THE CHARACTER GENERATOR IS TYPICALLY A ROM WHICH CONVERTS CHARACTER CODE INPUTS TO DOT MATRIX BITS AT THE OUTPUT.



### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

The 2530 is a high speed 4,096-bit Static Read-Only Memory available in a 512x8 organization. This device has TTL compatible inputs and outputs and requires +5V and -12V power supplies. A READ input controls the entry of data from the ROM into output latches. Three-state outputs allow OR tying for implementing larger memories. Two-mask programmable OUTPUT ENABLES control the eight output devices without affecting address circuitry.

#### FEATURES

- 512x8 ORGANIZATION
- 625ns TYPICAL ACCESS TIME
- STATIC OPERATION
- ADDRESS LATCHES
- PROGRAMMABLE OUTPUT ENABLES
- TTL/DTL COMPATIBLE INPUTS
- THREE-STATE OUTPUTS
- $V_{CC} = +5V$ ,  $V_{GG} = -12V$
- 24-PIN SILICONE DIP
- P-MOS SILICON GATE TECHNOLOGY

#### APPLICATIONS

- MICRO-PROGRAMMING
- CODE-CONVERSION
- PROGRAM STORAGE

#### TTL COMPATIBILITY

All inputs of the 2530 can be driven directly by standard bipolar integrated circuits, (TTL, DTL, etc.). The data output buffers are capable of sinking a minimum of 1.6mA sufficient to drive one standard TTL load.

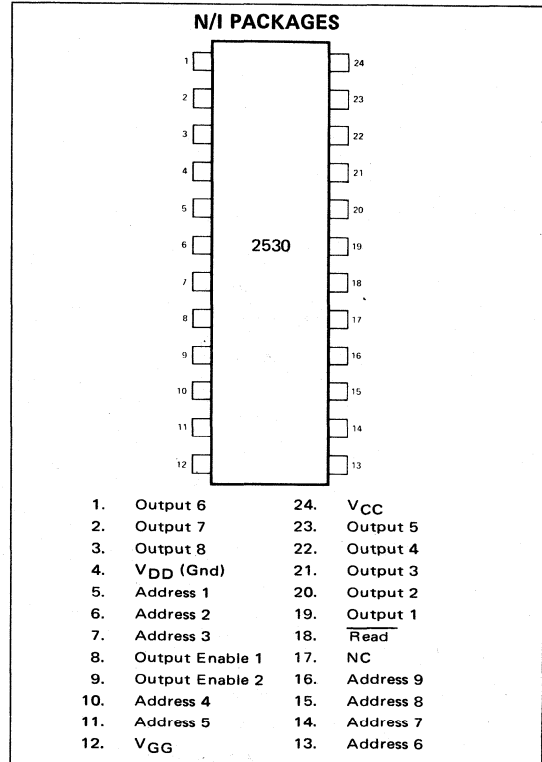
#### STANDARD TRUTH TABLES

The 2530NX/CM3530 is an ASCII-EBCDIC and EBCDIC-ASCII code converter. Use this device for evaluation or for applications requiring this conversion.

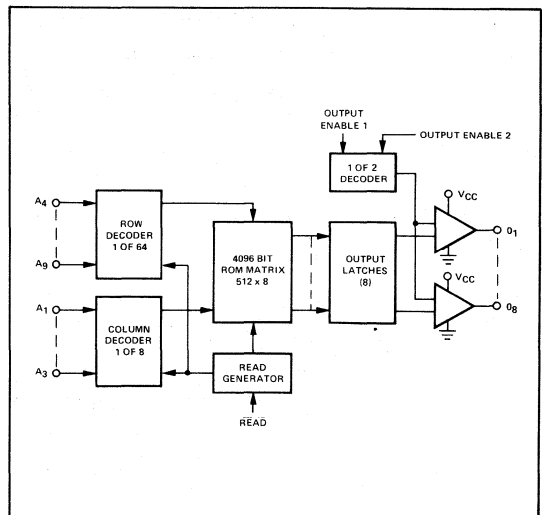
#### PART IDENTIFICATION

PART	OP. TEMP. RANGE	PACKAGE
2530N	0-70°C	24-Pin Silicone DIP
2530I	0-70°C	24-Pin Ceramic DIP

#### PIN CONFIGURATION (Top View)



#### BLOCK DIAGRAM



# SIGNETICS HIGH SPEED 512 X 8 STATIC READ-ONLY MEMORY ■ 2530

## MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature	0°C to 70°C	Package Power Dissipation <sup>2</sup> @ 70°C	730mW
Storage Temperature	-65°C to +150°C	Input <sup>3</sup> and Supply Voltages with respect to V <sub>CC</sub>	+0.3 to -20V

## DC CHARACTERISTICS

T<sub>A</sub> = 0° to +70°C; V<sub>CC</sub> = +5V ± 5%; V<sub>GG</sub> = -12V ± 5%; unless otherwise noted. (See notes 4, 5, 6, 7)

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
I <sub>LI</sub>	Input Load Current		10	500	nA	V <sub>IN</sub> = -5.5V T <sub>A</sub> = 25°C
I <sub>LO</sub>	Output Leakage Current		10	1000	nA	V <sub>OUT</sub> = 0V T <sub>A</sub> = 25°C V <sub>CE</sub> = V <sub>CC</sub>
I <sub>CC</sub>	V <sub>CC</sub> Power Supply Current		30	45	mA	(8)
I <sub>GG</sub>	V <sub>GG</sub> Power Supply Current		30	45	mA	(8)
V <sub>IL</sub>	Input Logic "0"	-5		+0.6	V	(13)
V <sub>IH</sub>	Input Logic "1"	+3.4		5.3	V	(13)

## AC CHARACTERISTICS

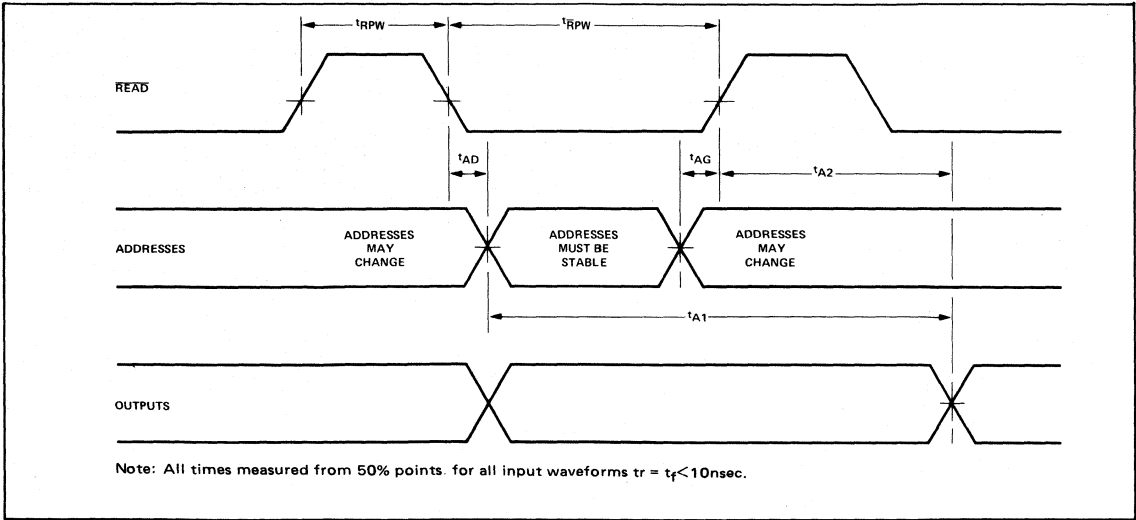
T<sub>A</sub> = 0°C to 70°C; V<sub>CC</sub> = 5V ± 5%; V<sub>GG</sub> = -12V ± 5%; unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
V <sub>OL</sub>	Output Logic "zero"			+0.5	V	I <sub>OL</sub> = 1.6mA
V <sub>OH</sub>	Output Logic "one"	+3.8			V	I <sub>OH</sub> = 100μA
t <sub>RPW11</sub>	Read Pulse Width	250	200		ns	
t <sub>RPW10</sub>	Read Pulse Width	500	400		ns	
t <sub>AD</sub>	Address Delay Time (12)			50	ns	
t <sub>AG</sub>	Address-Read Pulse Gap (12)			50	ns	
t <sub>A1</sub>	Address to Output Delay		625	700	ns	(9)
t <sub>A2</sub>	End of Read Pulse to Output Delay		200	250	ns	(9)
C <sub>IN</sub>	Address Input Capacitance			10	pF	f = 1MHz,
t <sub>OE</sub>	Output Enable to Output Delay		100	250	ns	V <sub>AC</sub> = 25mV p-p V <sub>IN</sub> = V <sub>CC</sub>

### NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a +150°C maximum junction temperature and a thermal resistance of 110°C/W junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and nominal supply voltages.
- Outputs Open, t<sub>RPW</sub> = 250ns, t<sub>RPW</sub> = 500ns.
- T<sub>A</sub> = 0°C to +70°C
- During t<sub>RPW1</sub> data is clocked into the output latches and the address decoders are precharged in preparation for the next cycle.
- During t<sub>RPW1</sub> addresses are decoded and sent to the memory matrix; and the stored memory data is moved to the data inputs of the output RS latches. This data is clocked into the output latches at the end (rising edge) of the READ pulse. After t<sub>A2</sub> data appears at the output terminals.
- Addresses must be stable within 50ns after the READ line falls and must remain stable until at least 50ns before the READ line goes high.
- Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.

TIMING DIAGRAM



2530 CUSTOM CODING INFORMATION

TRUTH TABLE INPUT:

A truth table may be submitted at a greater non-recurring cost to the customer. A format similar to the one shown below is satisfactory.

INPUT ADDRESS									DECIMAL ADDRESS	OUTPUT							
A <sub>9</sub>	A <sub>8</sub>	A <sub>7</sub>	A <sub>6</sub>	A <sub>5</sub>	A <sub>4</sub>	A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>		O <sub>8</sub>	O <sub>7</sub>	O <sub>6</sub>	O <sub>5</sub>	O <sub>4</sub>	O <sub>3</sub>	O <sub>2</sub>	O <sub>1</sub>
0	0	0	0	0	0	0	0	0	000								
0	0	0	0	0	0	0	0	1	001								
1	1	1	1	1	1	1	1	0	510								
1	1	1	1	1	1	1	1	1	511								

Plus Output Enable 1 and 2 coding.

# SIGNETICS HIGH SPEED 512 X 8 STATIC READ-ONLY MEMORY ■ 2530

## 2530 CUSTOM CODING INFORMATION

### PUNCHED CARD INPUT

#### Header Card

Card No.	Column	Information
1	1-5	"2530N" or "2530I"
	6-14	Blank
	15-19	"CODED"
	20	Blank
	21	Logic state of Output Enable #2, (CS2) - Most Significant Bit.
	22	Logic state of Output Enable #1.
	23	Blank
	24-71	Customer company name.
	72	Blank
	73-80	Date

#### Data Cards:

Card No.	Column	Information
1	1-3	Decimal address (blank, blank, 0.)
	4	Blank
	5-12	8-digit binary output (MSB-left)
	13-20	Blank
	21-33	Decimal address, (blank, blank, 1.)
	24	Blank
	25-32	8-Digit binary output (MSB-left)
	33-40	Blank
	41-43	Decimal address, (Blank, blank, 2.)
	44	Blank
	45-52	8-digit binary output (MSB-left)
	53-60	Blank
	61-63	Decimal address, (Blank, blank, 3.)
	64	Blank
	65-72	8-digit binary output (MSB-left)
	73-80	Blank
	2 ⋮ 128	

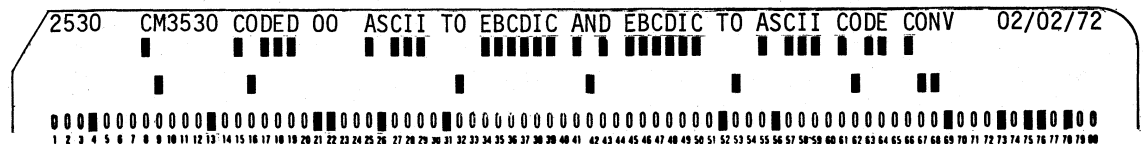
#### I.D./Comment Cards:

Card No.	Column	Information
1	1	"C"
	2	Blank
	3-80	Person responsible for reviewing Signetics truth table and Company Name.
2	1	"C"
	2	Blank
	3-80	Customer Street Address
3	1	"C"
	2	Blank
	3-80	Customer City, State, Zip.

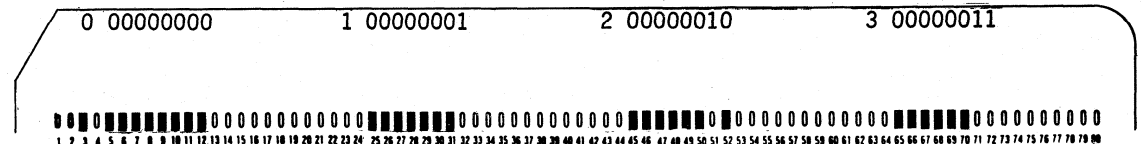
NOTE: MSB = 0<sub>9</sub>

#### EXAMPLES:

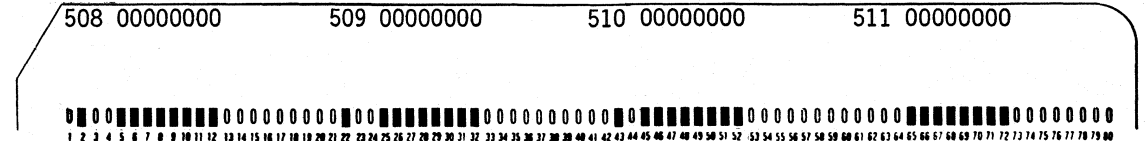
##### Header Card



##### First Data Card



##### Last Data Card



### SILICON GATE MOS 2500 SERIES

#### DESCRIPTION

The Signetics 2532 Static Shift Register consists of enhancement mode P-Channel silicon gate MOS devices integrated on a single monolithic chip. Each of the four 80-bit registers is provided with an independent input, push-pull output and recirculation control. The single phase clock is common to all four registers. All inputs and outputs including the clock interface directly with TTL or DTL circuits without external components.

Data is entered when the clock is at a logic "1". Data is shifted when the clock goes low. When the Recirculate control is at a logic "1", data recirculates and is continuously available at the output, data input is inhibited. With the Recirculate control is at a logic "0", data is entered.

#### FEATURES

- TOTAL TTL COMPATIBILITY
- SINGLE CLOCK LINE
- RECIRCULATE PATH ON CHIP
- DC TO 1.5 MHz OPERATION GUARANTEED
- LOW POWER (TYPICALLY 400  $\mu$ W/BIT)
- PIN-FOR-PIN REPLACEMENT FOR (DYNAMIC) MK1007P AND TMS3409
- POWER SUPPLIES +5V AND -12V

#### APPLICATIONS

- LOW COST SEQUENTIAL ACCESS MEMORIES
- LOW COST STATIC BUFFER MEMORIES
- CRT REFRESH MEMORIES - LINE STORAGE
- DELAY LINES
- DIGITAL FILTERING

#### SPECIAL FEATURES

The three clock phases used by the static register cells are generated internally by an on-chip generator. This clock generator is controlled by a single TTL/DTL logic level input.

#### BIPOLAR COMPATIBILITY

All inputs of these registers, including the clock can be driven directly by bipolar TTL/DTL integrated circuits without external components. Outputs are push-pull operating between 0V and +5V and provide a sink current of 1.6mA for a fanout of one TTL load.

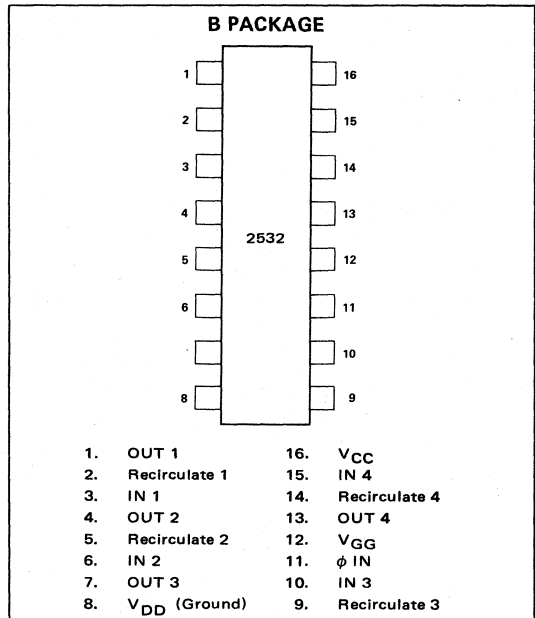
#### PART IDENTIFICATION

PART NUMBER	BIT LENGTH	PACKAGE
2532B	Quad 80	16-Pin DIP

#### MAXIMUM GUARANTEED RATINGS (1)

Operating Ambient Temperature (2)	0°C to +70°C
Storage Temperature	-65°C to +150°C
Package Power Dissipation at T <sub>A</sub> = 70°C	640 mW

#### PIN CONFIGURATION (Top View)

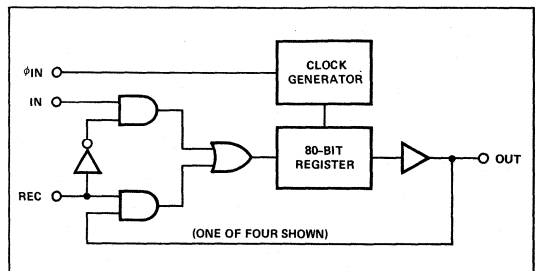


#### TRUTH TABLE

RECIRCULATE	INPUT	FUNCTION
0	0	"0" is Written
0	1	"1" is Written
1	0	Recirculate
1	1	Recirculate

NOTE: "0" = 0V, "1" = +5V

#### BLOCK DIAGRAM



Data and Clock Input Voltages and Supply Voltages with respect to V<sub>CC</sub>

+0.3V to -20V

**SIGNETICS QUAD 80-BIT STATIC SHIFT REGISTER ■ 2532**
**DC CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ;  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$  unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$I_{LI}$	Input Load Current		10	500	nA	$V_{IN} = 5.5\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{LC}$	Clock Leakage Current		10	500	nA	$V_{ILC} = 0\text{V}$ , $T_A = 25^\circ\text{C}$
$I_{GG}$	Power Supply Current		6	10	mA	Continuous Operation $F = 1.5\text{ MHz}$ , $T_A = 25^\circ\text{C}$ Outputs Open
$I_{CC}$	Power Supply Current		12	20	mA	
$V_{IL}$	Input "Low" Voltage			+0.6	V	Note 8
$V_{IH}$	Input "High" Voltage	+3.4		5.3	V	Note 8
$V_{ILC}$	Clock Input "Low" Voltage			+0.6	V	Note 8
$V_{IHC}$	Clock Input "High" Voltage	+3.4		5.3	V	Note 8

**AC CHARACTERISTICS**  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ ;  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$ .  
 (CONDITIONS OF TEST Input rise and fall times: 10 nsec. Output load is 1 TTL Gate.)

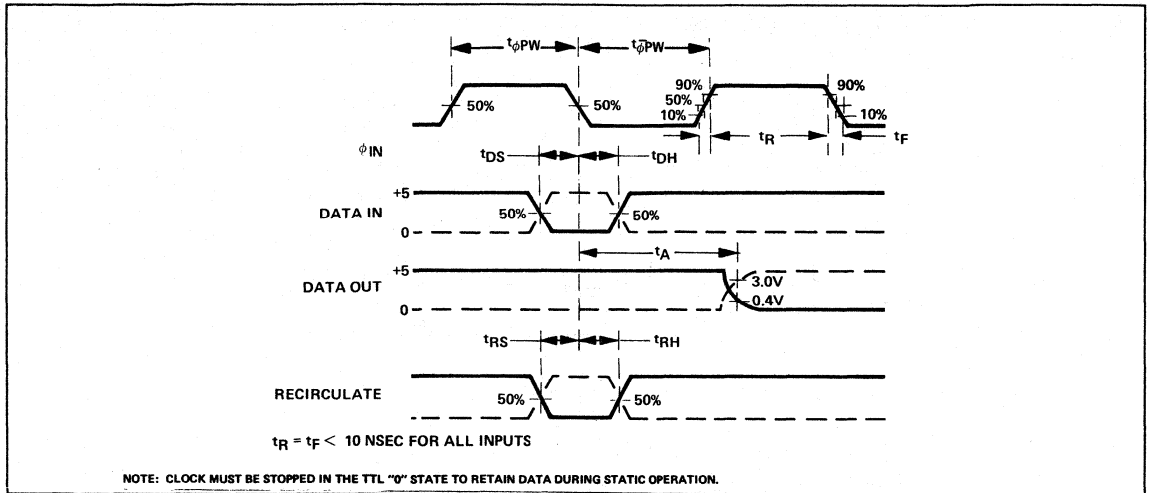
SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
Frequency	Clock Rep Rate	DC	3.0	1.5	MHz	See Timing Diagram note
$t_{\phi PW}$	Clock Pulse Width	0.33		100	$\mu\text{s}$	
$\overline{t_{\phi PW}}$	Clock Pulse Width	0.33		DC	$\mu\text{s}$	
$t_R, t_F$	Clock Pulse Transition			5	$\mu\text{s}$	
$t_{DS}$	Data Set-up Time	120			ns	
$t_{DH}$	Data Hold Time	0			ns	$I_{OL} = 1.6\text{mA}$
$t_A$	Clock to Data Out Delay			400	ns	
$t_{RS}$	Recirculate Set-up Time	150			ns	
$t_{RH}$	Recirculate Hold Time	0			ns	
$C_{IN}$	Input Capacitance			5	pF	@ 1 MHz; $V_{IN} = V_{CC}$ ; $V_{AC} = 25\text{mV p-p}$
$C_{\phi}$	Clock Capacitance			5	pF	@ 1 MHz; $V_{\phi} = V_{CC}$ ; $V_{AC} = 25\text{mV p-p}$
$V_{OL}$	Output "Low" Voltage			+0.5	V	$I_{OL} = 1.6\text{mA}$
$V_{OH}$	Output "High" Voltage	+3.8			V	$I_{OH} = 100\mu\text{A}$

**NOTES:**

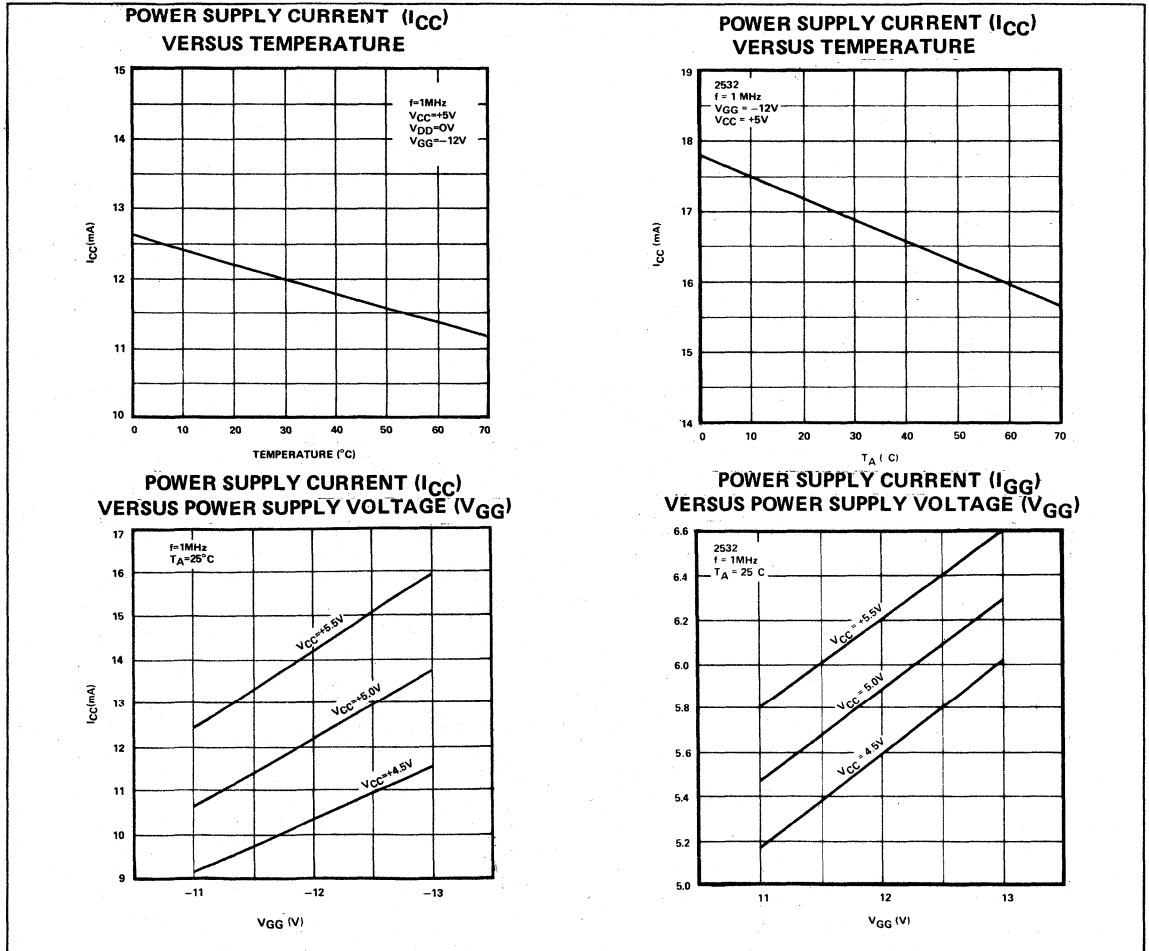
- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a  $+150^\circ\text{C}$  maximum junction temperature and a thermal resistance of  $125^\circ\text{C/W}$  junction to ambient.
- All inputs are protected against static charge.

- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at  $+25^\circ\text{C}$  and nominal supply voltages.
- Guaranteed input levels are stated for worst case conditions including a  $\pm 5\%$  variation in  $V_{CC}$  and a temperature variation of  $0^\circ\text{C}$  to  $+70^\circ\text{C}$ . Actual input requirements with respect to  $V_{CC}$  are  $V_{IH} = V_{CC} - 1.85\text{V}$  and  $V_{IL} = V_{CC} - 4.15\text{V}$ .

**TIMING DIAGRAM**

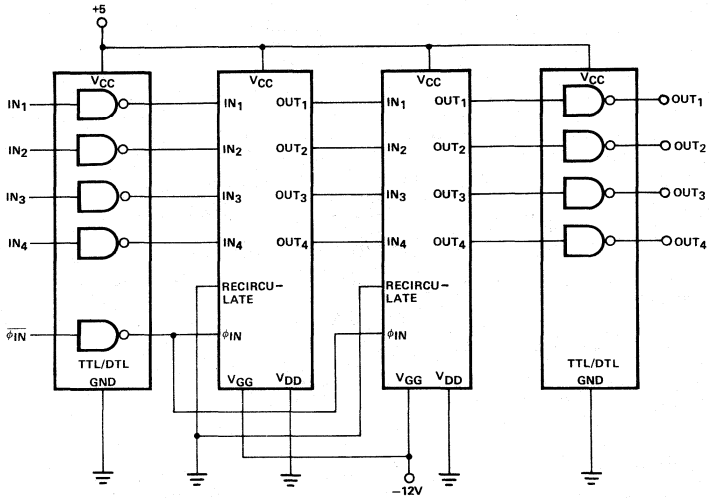


**TYPICAL CHARACTERISTIC CURVES**

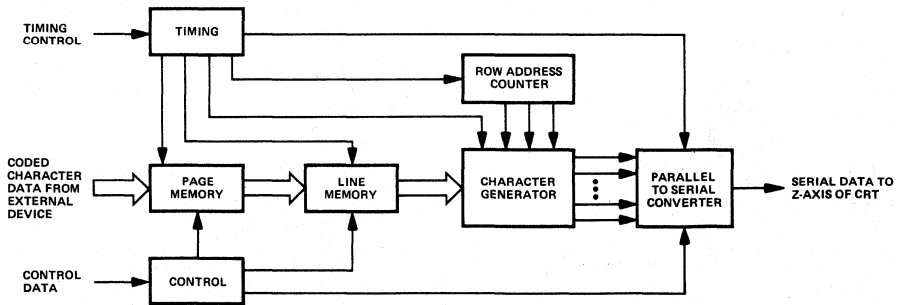


APPLICATIONS INFORMATION

DTL/TTL – MOS – MOS – DTL/TTL INTERFACING



NOTE: All unused inputs must be tied to a "1" or a "0", i.e., MOS inputs cannot be left floating.



PAGE MEMORY: THIS MEMORY CONTAINS CHARACTER CODES. TYPICALLY, IT CONTAINS THE SAME NUMBER OF CHARACTER CODES AS THE NUMBER OF CHARACTER ON A FULL SCREEN.  
 LINE MEMORY: THIS MEMORY CONTAINS THE CHARACTER CODES FOR ONE LINE OF THE CRT DISPLAY.  
 CHARACTER GENERATOR: THE CHARACTER GENERATOR IS TYPICALLY A ROM WHICH CONVERTS CHARACTER CODE INPUTS TO DOT MATRIX BITS AT THE OUTPUT.

NOTE: THE 2532 IS VERY WELL SUITED FOR USE AS A LINE MEMORY.



## SILICON GATE MOS 2500 SERIES

### DESCRIPTION

The Signetics 2533 Static Shift Register consists of enhancement mode P-channel silicon gate MOS devices integrated on a single monolithic chip.

The 1024-bit register is equipped with two data inputs together with a "Stream Select" control to facilitate external recirculation.

The single phase clock input, data input, data output, and stream select control will interface directly with TTL/DTL circuits without external components.

Data is entered when the clock is at a logic "1". Data is shifted when the clock goes low.

### FEATURES

- TOTAL TTL COMPATIBILITY
- SINGLE CLOCK LINE
- DC TO 1.5MHz GUARANTEED
- LOW POWER (TYPICALLY 250 $\mu$ W/BIT)
- POWER SUPPLIES +5V AND -12V
- 8-PIN DIP
- STREAM SELECT FOR EASY RECIRCULATION

### APPLICATIONS

LOW COST SEQUENTIAL ACCESS MEMORIES  
 LOW COST STATIC BUFFER MEMORIES  
 CRT REFRESH - PAGE MEMORY  
 DELAY LINES  
 DRUM MEMORY REPLACEMENT

### SPECIAL FEATURES

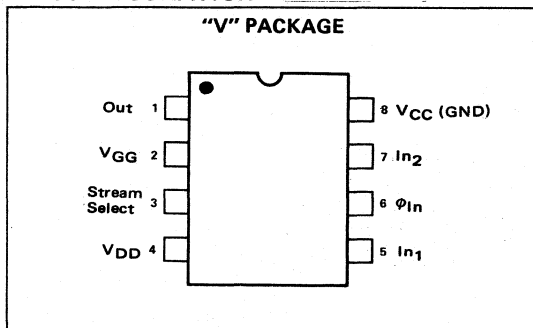
The three clock phases used in the static register cells are generated internally by an on-chip generator. This clock generator is controlled by a single TTL/DTL logic level input.

Recirculation of data in the 2533 is accomplished by simply jumpering the output back to In 2. The stream select control then becomes a Data Entry/Recirculate Control.

### BIPOLAR COMPATIBILITY

All inputs of this register, including the clock, can be driven directly by bipolar TTL/DTL integrated circuits without external components. The output is push-pull, operating between 0V and +5V, and provides a sink current of 1.6mA for a fanout of one TTL load.

### PIN CONFIGURATION (Top View)

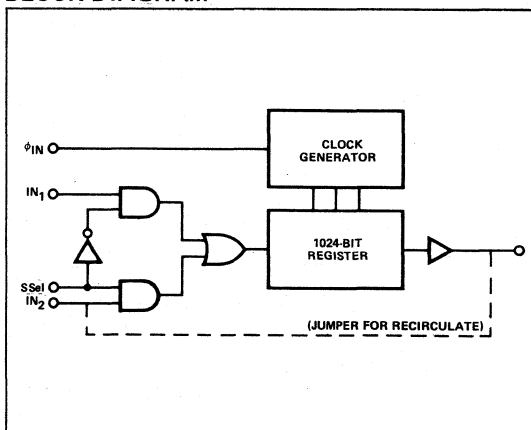


### TRUTH TABLE

STREAM SELECT	FUNCTION
0	IN 1 SELECTED
1	IN 2 SELECTED

NOTE: "0" = 0V, "1" = +5V

### BLOCK DIAGRAM



### PART IDENTIFICATION TABLE

PART NUMBER	BIT LENGTH	PACKAGE
2533 V	1024	8-Pin DIP

### MAXIMUM GUARANTEED RATINGS<sup>(1)</sup>

Operating Ambient Temperature <sup>(2)</sup>	0°C to +70°C
Storage Temperature	-65°C to +150°C
Power Dissipation (Note 2)	535mW @ T <sub>A</sub> > 25°C
Data and Clock Input Voltages and Supply Voltages with Respect to V <sub>CC</sub>	+0.3V to -20V

DC CHARACTERISTICS

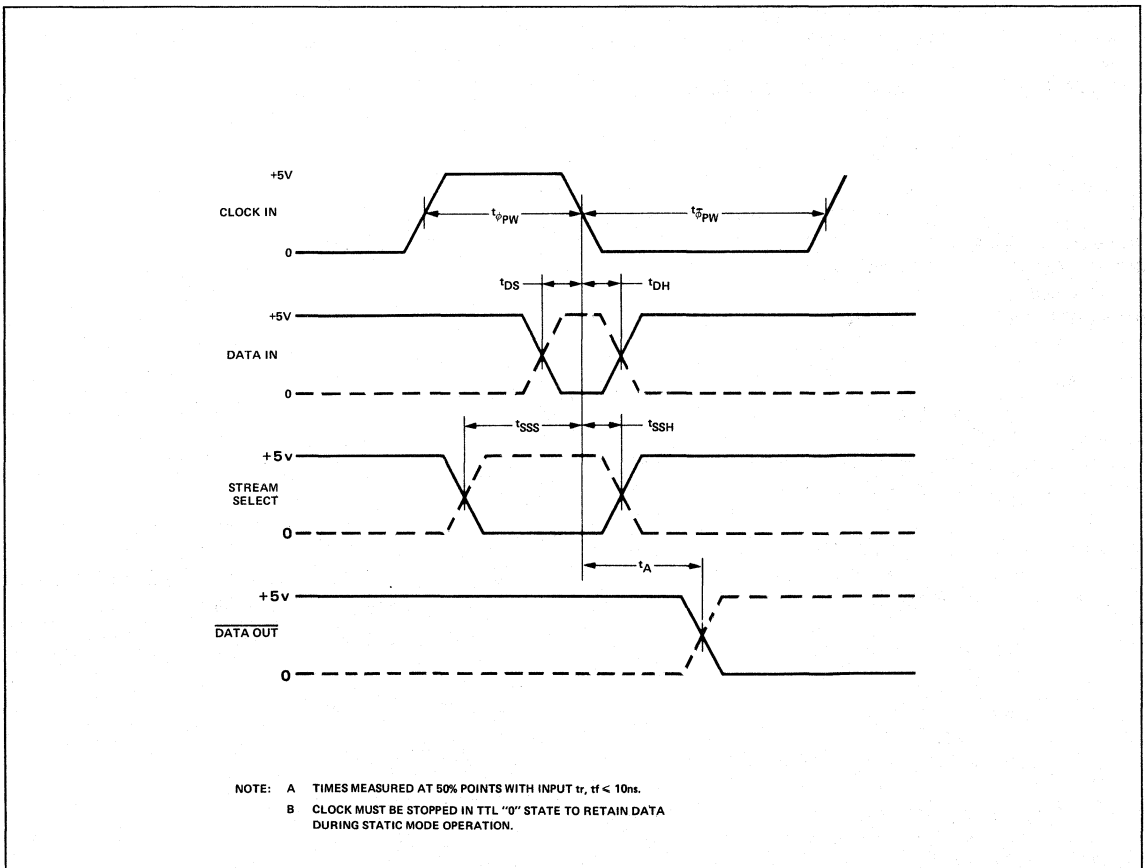
( $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ;  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$  unless otherwise noted.)

SYMBOL	TEST	MIN.	TYP.	MAX.	UNITS	CONDITIONS
I <sub>LI</sub>	Input Load Current		10	500	nA	$V_{IN} = 0, T_A = 25^\circ\text{C}$
I <sub>LC</sub>	Clock Leakage Current		10	500	nA	$V_{ILC} = \text{GND}, T_A = 25^\circ\text{C}$
I <sub>CC</sub>	Power Supply Current		16	30	mA	Continuous Operation F = 1.5MHz
I <sub>GG</sub>	Power Supply Current		5.0	7.5	mA	
V <sub>IL</sub>	Input "Low" Voltage			+0.6	V	Note 8 V <sub>CC</sub> = +5V
V <sub>IH</sub>	Input "High" Voltage	+3.4		5.3	V	
V <sub>ILC</sub>	Clock Input "Low" Voltage			+0.6	V	
V <sub>IHC</sub>	Clock Input "High" Voltage	+3.4		5.3	V	
					V	

NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated corresponding to a thermal resistance of 150°C/W junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at +25°C and nominal supply voltages.
- Guaranteed input levels are stated for worst case conditions including a ±5% variation in V<sub>CC</sub> and a temperature variation of 0°C to +70°C. Actual input requirements with respect to V<sub>CC</sub> are V<sub>IH</sub> = V<sub>CC</sub> - 1.85V and V<sub>IL</sub> = V<sub>CC</sub> - 4.15V.

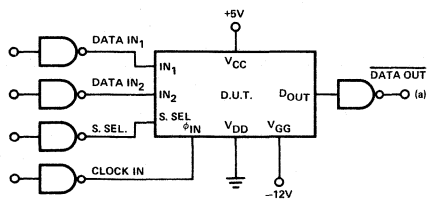
TIMING DIAGRAM



AC CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ ,  $V_{CC} = +5\text{V} \pm 5\%$ ;  $V_{GG} = -12\text{V} \pm 5\%$ ).

SYMBOL	TEST	MIN.	TYP.	MAX.	UNITS	CONDITIONS
Frequency	Clock & Data Rep Rate		2	1.5	MHz	
$t_{\phi PW}$	Clock Pulse Width	.350		100	$\mu\text{s}$	See Timing Diagram Note
$t_{\phi PW}$	Clock Pulse Width	250			ns	
$t_r, t_f$	Clock Pulse Transition			1	$\mu\text{s}$	
$t_{DW}$	Data Write Set-Up Time	50			ns	
$t_{DH}$	Data to Clock Hold Time	50			ns	
$t_A$	Clock to Data Out Delay		200	300	ns	
$t_{SSH}$	Stream Select Hold Time	50			ns	
$t_{SSS}$	Stream Select Set-Up Time	80			ns	
$C_{IN}$	Input Capacitance			5	pF	@ 1 MHz, $V_{IN} = V_{CC}$ $V_{AC} = 25\text{mV p-p}$
$C_{OUT}$	Output Capacitance			5	pF	@ 1 MHz, $V_{OUT} = V_{CC}$ $V_{AC} = 25\text{mV p-p}$
$C_{\phi}$	Clock Capacitance			5	pF	@ 1 MHz, $V_{\phi} = V_{CC}$ $V_{AC} = 25\text{mV p-p}$
$V_{OL}$	Output "Low" Voltage			+0.5	V	$I_{OL} = 1.6\text{mA}$
$V_{OH}$	Output "High" Voltage	+3.8			V	$I_{OH} = 100\mu\text{A}$

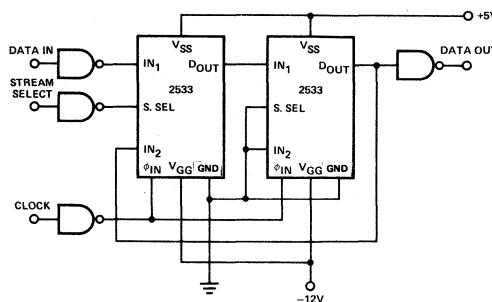
A.C. TEST SETUP



NOTES:  
Measure  $t_A$  between device input and point (a).  
Gates are standard 7400.

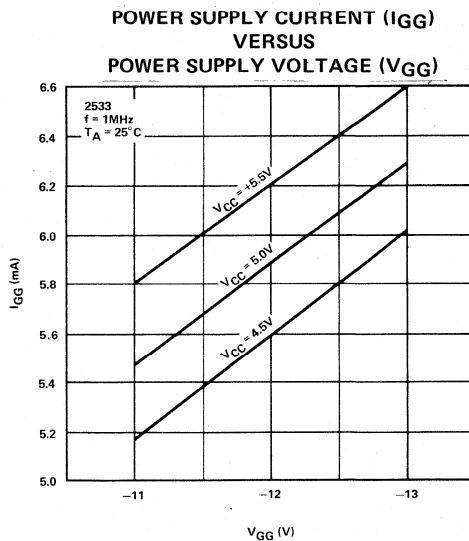
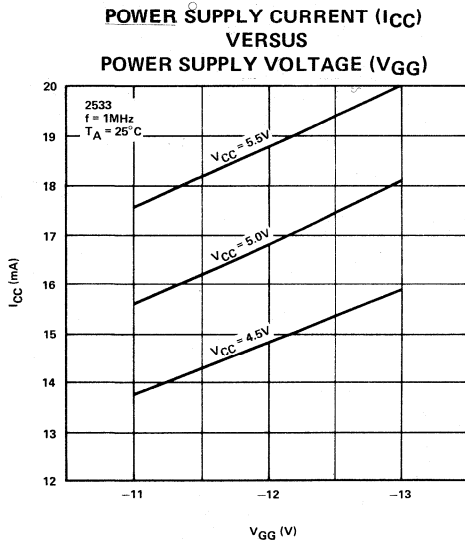
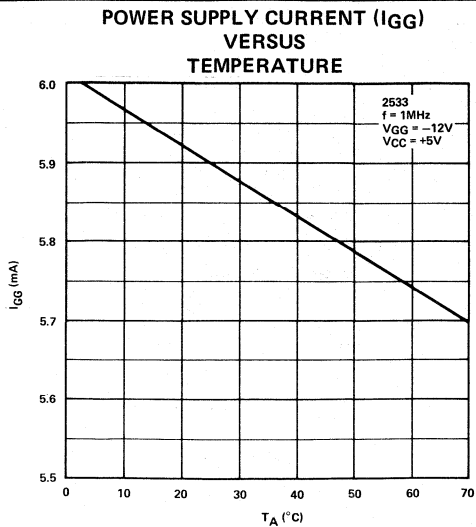
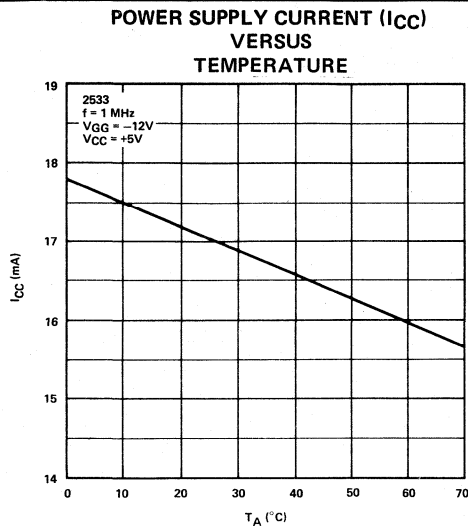
APPLICATIONS INFORMATION

2048-BIT STORAGE REGISTER WITH RECIRCULATE



NOTE:  
Gates are standard DTL or TTL.

TYPICAL CHARACTERISTIC CURVES



## PRELIMINARY SPECIFICATION

## SILICON GATE MOS 2500 SERIES

### DESCRIPTION

The 2580 is an 8,192-Bit Read-Only Memory available in a 2048x4 organization. This device has TTL compatible inputs and outputs and requires +5V and -12V power supplies. A READ input controls the entry of data from the ROM into output latches. Three-state outputs allow OR tying for implementing larger memories. The outputs are enabled by a programmable four bit select code applied to four binary chip select terminals.

### FEATURES

- 2048x4 ORGANIZATION
- 625ns TYPICAL ACCESS TIME
- OUTPUT LATCHES
- 1 OF 16 CHIP ENABLE DECODING
- TTL/DTL COMPATIBLE INPUTS AND OUTPUTS
- THREE-STATE OUTPUTS
- $V_{CC} = +5V$ ,  $V_{GG} = -12V$ ,  $V_{DD} = 0V$
- 24 PIN SILICONE DIP
- P-MOS SILICON GATE TECHNOLOGY

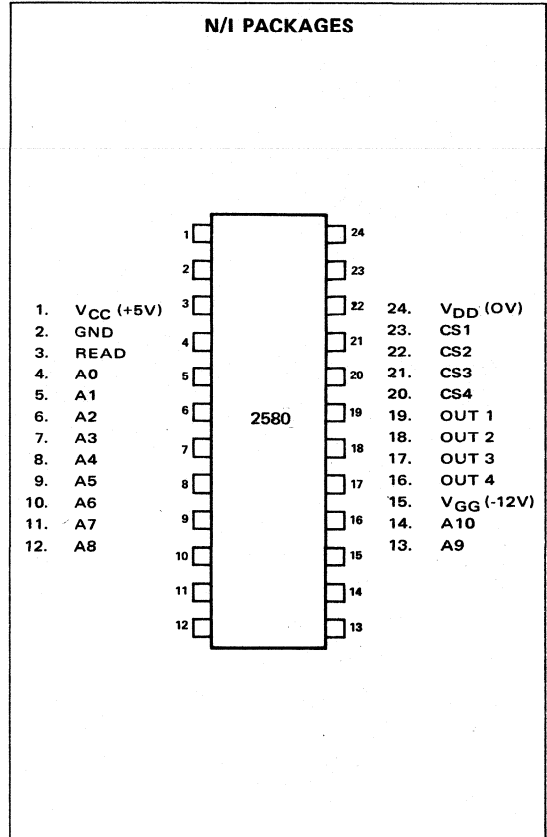
### APPLICATIONS

MICRO-PROGRAMMING  
LOOK-UP TABLES  
DATA STORAGE  
CODE CONVERSION  
RANDOM LOGIC SYNTHESIS  
CHARACTER GENERATION  
PROGRAM STORAGE

### BIPOLAR COMPATIBILITY

All inputs of the 2580 can be driven directly by standard TTL level signals. The data output buffers are capable of sinking a minimum of 1.6mA sufficient to drive one standard TTL load.

### PIN CONFIGURATION (Top View)



### PART IDENTIFICATION

PART NUMBER	OP. TEMP. RANGE	PACKAGE
2580N	0-70°C	24-PIN SILICONE DIP
2580I	0-70°C	24-PIN CERAMIC DIP

Note: "0" = 0V, "1" = +5V

# SIGNETICS 8192-BIT READ-ONLY MEMORY ■ 2580

## DC CHARACTERISTICS

$T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ;  $V_{CC} = +5V \pm 5\%$ ,  $V_{DD} = 0V$ ,  $V_{GG} = -12V \pm 5\%$  unless otherwise noted. (See notes 4, 5, 6, 7)

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$I_{LI}$	Input Load Current		10	500	nA	$V_{IN} = -5.5V$ $T_A = 25^\circ\text{C}$
$I_{LO}$	Output Leakage Current		10	1000	nA	$V_{OUT} = 0V$ $T_A = 25^\circ\text{C}$ $V_{CE} = V_{CC}$
$I_{CC}$	$V_{CC}$ Power Supply Current		23	35	mA	(8)
$I_{GG}$	$V_{GG}$ Power Supply Current		23	35	mA	(8)
$V_{IL}$	Input Logic "0"			+0.6	V	} Note 12
$V_{IH}$	Input Logic "1"	+3.4		5.3	V	

## AC CHARACTERISTICS

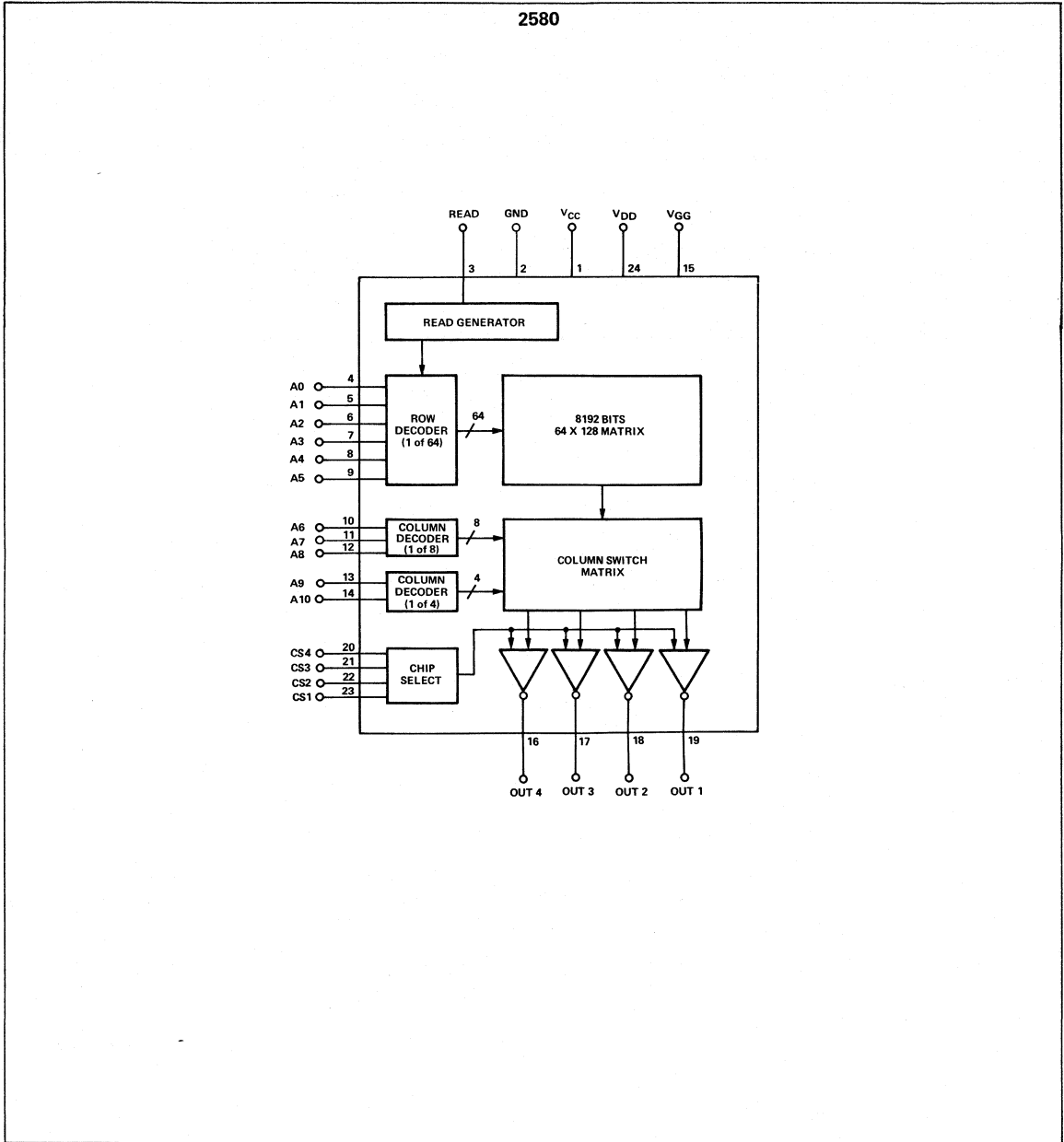
$T_A = 25^\circ\text{C}$ ;  $V_{CC} = 5V \pm 5\%$ ,  $V_{DD} = 0V$ ,  $V_{GG} = -12V \pm 5\%$  unless otherwise noted.

SYMBOL	TEST	MIN	TYP	MAX	UNIT	CONDITIONS
$V_{OL}$	Output Logic "0"			+0.5	V	$I_{OI} = 1.6\text{mA}$ $I_{OH} = 100\mu\text{A}$
$V_{OH}$	Output Logic "1"	+3.8			V	
$t_{RPW}^{10}$	Read Pulse Width	650	500		ns	
$t_{\overline{RPW}}^9$	$\overline{\text{Read}}$ Pulse Width	500	400		ns	
$t_{AD}$	Address Delay Time (11)			50	ns	
$t_{AH}$	Address Hold Time	0			ns	
$t_{A1}$	Address to Output Delay		625	950	ns	
$t_{A2}$	End of Read Pulse to Output Delay		250	350	ns	
$C_{IN}$	Input Capacitance			10	pF	$f = 1\text{MHz}$ , $V_{AC} = 25\text{mV p-p}$ $V_{IN} = V_{CC}$

### NOTES:

- Stresses above those listed under "Maximum Guaranteed Rating" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a  $+150^\circ\text{C}$  maximum junction temperature and a thermal resistance of  $110^\circ\text{C/W}$  junction to ambient.
- All inputs are protected against static charge.
- Parameters are valid over operating temperature range unless specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at  $+25^\circ\text{C}$  and nominal supply voltages.
- Outputs open,  $t_{RPW} = 500\text{ns}$ ,  $t_{\overline{RPW}} = 500\text{ns}$ .
- During  $t_{RPW}$  data is clocked into the output latches and the address decoders are precharged in preparation for the next cycle.
- During  $t_{RPW}$  addresses are decoded and sent to the memory matrix; and the stored memory data is moved to the data inputs of the output RS latches. This data is clocked into the output latches at the end (falling edge) of the READ pulse. After  $t_{A2}$ , data appears at the output terminals.
- Addresses must be stable within 50ns after the READ line rises and must remain stable until the READ line falls.
- Guaranteed input levels are stated for worst case conditions including a  $\pm 5\%$  variation in  $V_{CC}$  and a temperature variation of  $0^\circ\text{C}$  to  $+70^\circ\text{C}$ . Actual input requirements with respect to  $V_{CC}$  are  $V_{IH} = V_{CC} - 1.85V$  and  $V_{IL} = V_{CC} - 4.15V$ .

BLOCK DIAGRAM



(1)

Operating Ambient Temperature  
Storage Temperature

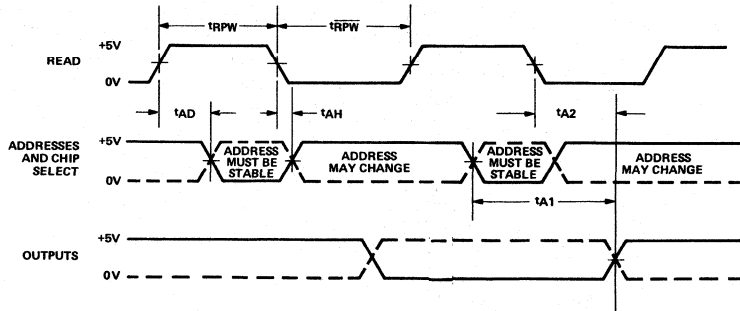
0° C to 70° C  
-65° C to +150° C

Package Power Dissipation<sup>2</sup> @ 70° C  
Input<sup>3</sup> and Supply Voltages  
with respect to V<sub>CC</sub>

730mW  
+0.3 to -20V

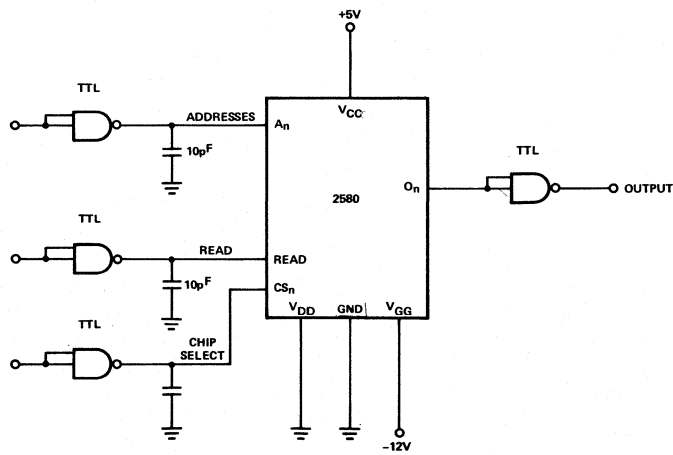
**SIGNETICS 8192-BIT READ-ONLY MEMORY ■ 2580**

**TIMING DIAGRAM**



Note: All measurements made at 50% points.  
Input  $t_r = t_f = 10ns$ .

**AC TEST SETUP**



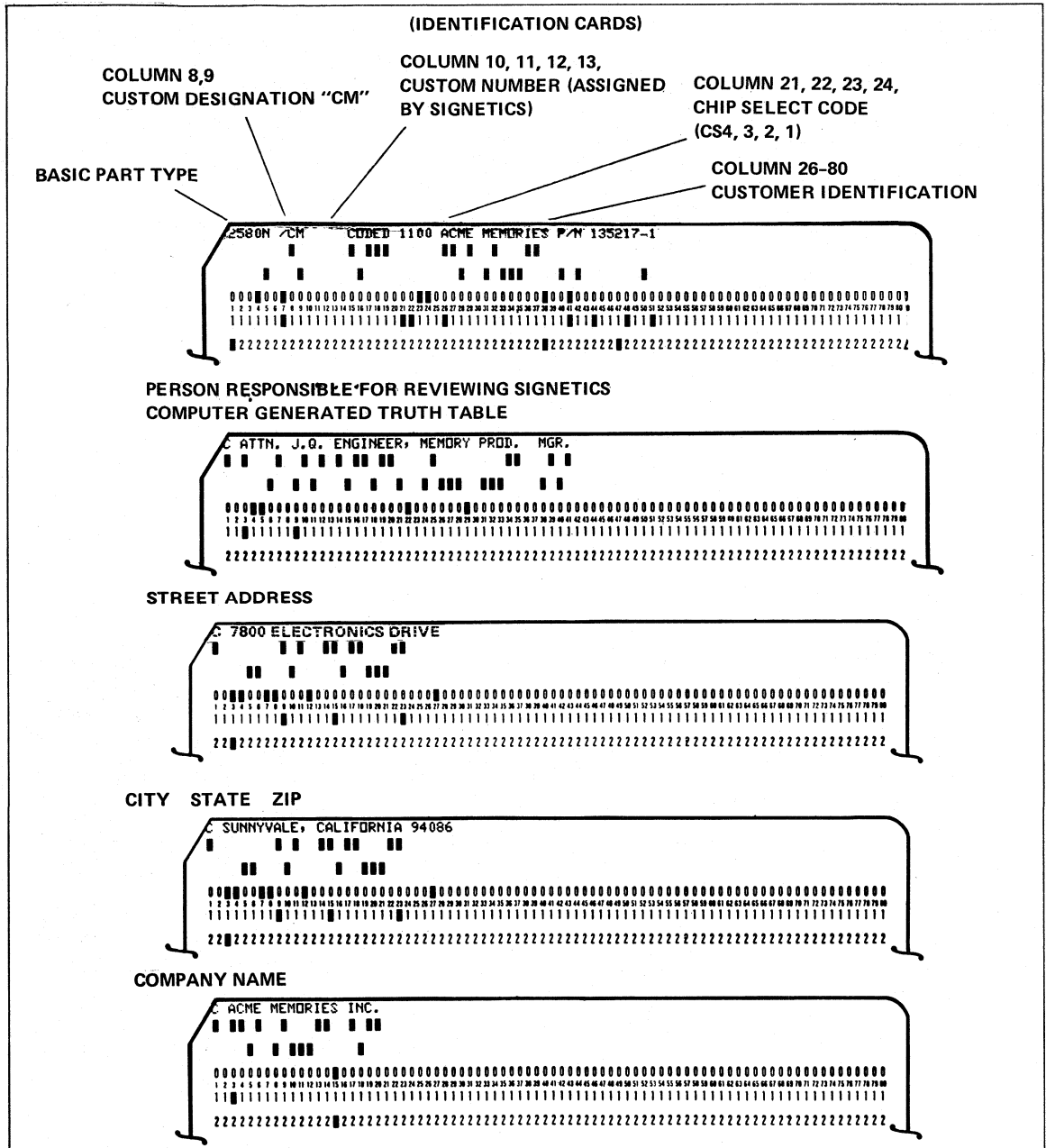


**CODING FORMAT**

Coding data for the 2580 may be sent to Signetics via punched cards or via a written truth table. Cards are preferred since errors are essentially eliminated.

On receipt of a card deck, Signetics will translate the card deck to a truth table using the Signetics Computer Aided Design (CAD) facility. The truth table will then be sent to the customer requesting engineer for final approval. On receipt of final approval, Signetics will cut the rubyolith mask and proceed with manufacture.

**CARD FORMAT**





## SILICON GATE MOS 2600 SERIES

### DESCRIPTION

The Signetics 2602 is a static random access read/write memory offering a 1024x1 organization. Fabricated with low threshold N-Channel silicon gate technology, the 2602 offers an access and read cycle time of less than 1 $\mu$ s. Write cycle time is 1 $\mu$ s.

The 2602 is fully static, requiring no clocks and is completely DTL/TTL compatible including the single +5V power supply requirement.

A faster version of this device is available. See the 2602-1 data sheet.

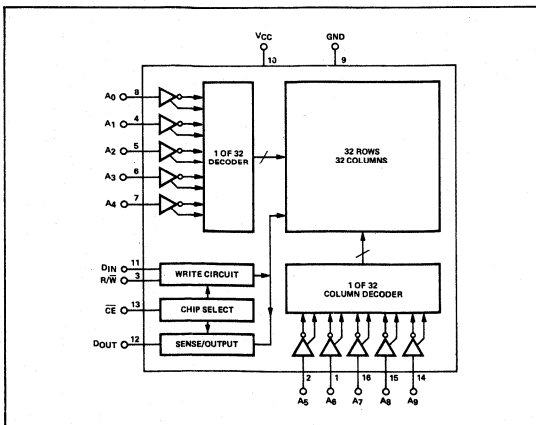
### FEATURES

- 1024x1 ORGANIZATION
- COMPLETELY STATIC OPERATION
- +5 VOLT POWER SUPPLY ONLY
- TTL COMPATIBLE INPUTS
- THREE-STATE TTL OUTPUT
- 16-PIN DIP PACKAGE
- 200mW DISSIPATION TYP.
- N-CHANNEL SILICON GATE
- NO CLOCKS, NO REFRESHING, NO SENSING
- 1 $\mu$ s ACCESS AND CYCLE TIMES

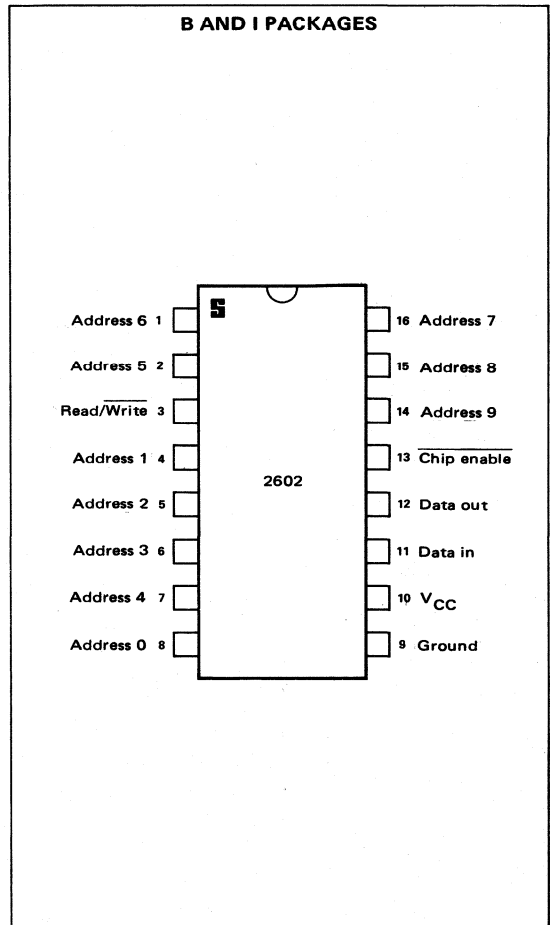
### APPLICATIONS

PERIPHERAL MEMORIES  
BUFFER MEMORIES  
MINICOMPUTER MEMORY

### BLOCK DIAGRAM



### PIN CONFIGURATION



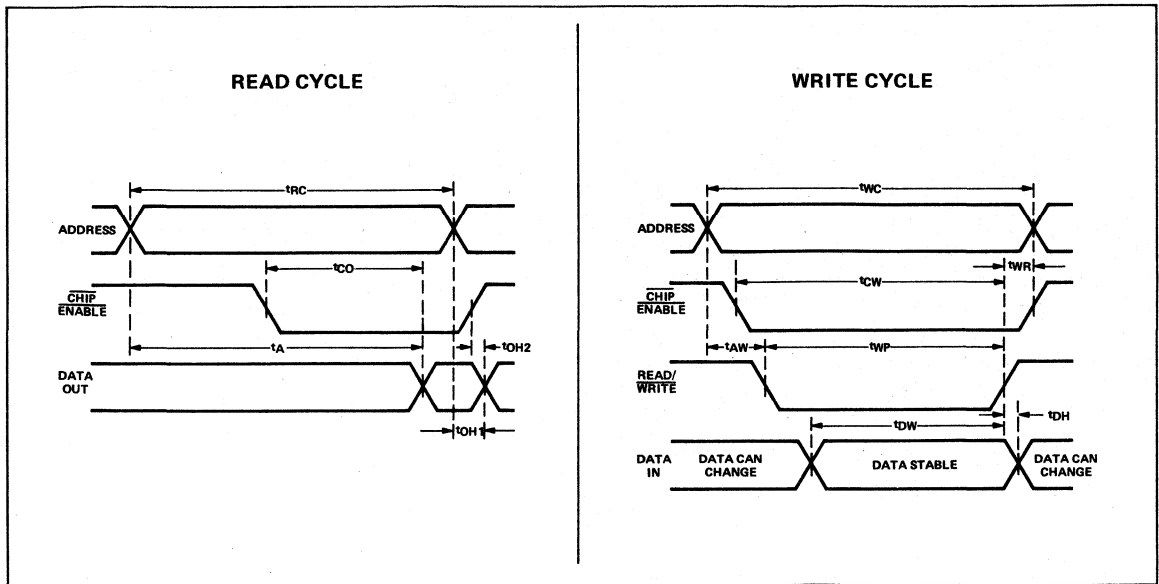
### MAXIMUM GUARANTEED RATINGS(1)

Operating Ambient Temperature	0°C to +70°C
Storage Temperature	-65°C to +150°C
All Input, Output, and Supply Voltages	-0.5 V to +7 V
with respect to ground	
Package Power Dissipation (2) "B" Pkg.	640 mW
"I" Pkg.	800 mW

### PART IDENTIFICATION

TYPE	PACKAGE	t <sub>ACCESS</sub>	OP. TEMP. RANGE
2602B	16-Pin Plastic DIP	1 $\mu$ s	0-70°C
2602I	16-Pin Ceramic DIP	1 $\mu$ s	0-70°C

TIMING DIAGRAMS



A.C. CHARACTERISTICS  $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ ,  $V_{CC} = 5\text{ V} \pm 5\%$  unless otherwise specified. See Notes 4, 5, 6, 7.

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	TYP	MAX	
<b>READ CYCLE</b>					
tRC	Read cycle	1000			ns
tA	Access time		500	1000	ns
tCO	Chip enable to output time		200	500	ns
tOH1	Previous read data valid with respect to address	50			ns
tOH2	Previous read data valid with respect to chip enable	0			ns
<b>WRITE CYCLE</b>					
tWC	Write cycle	1000			ns
tAW	Address to write setup time	200	100		ns
tWP	Write pulse width	750			ns
tWR	Write recovery time	50			ns
tDW	Data setup time	800			ns
tDH	Data hold time	100			ns
tCW	Chip enable to write setup time	900			ns

A.C. CONDITIONS OF TEST

Input Pulse Levels: +0.65 Volt to +2.2 Volt  
 Input Pulse Rise and Fall Times: 20nsec  
 Timing Measurement Reference Level: 1.5 Volt  
 Output Load: 1 TTL Gate and  $C_L = 100\text{ pF}$

D.C. OPERATING CHARACTERISTICS  $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{CC} = 5\text{ V} \pm 5\%$  unless otherwise specified. See Notes 4, 5, 6, 7, 8.

SYMBOL	PARAMETER	LIMITS			UNIT	TEST CONDITIONS
		MIN	TYP	MAX		
$I_{LI}$	Input load current (All input pins)			10	$\mu\text{A}$	$V_{IN} = 0$ to $5.25\text{V}$
$I_{LOH}$	Output leakage current			10	$\mu\text{A}$	$\overline{CE} = 2.2\text{V}$ , $V_{OUT} = 4.0\text{V}$
$I_{LOL}$	Output leakage current			-100	$\mu\text{A}$	$\overline{CE} = 2.2\text{V}$ , $V_{OUT} = 0.45\text{V}$
$I_{CC1}$	Power supply current		30	60	$\text{mA}$	All inputs = $5.25\text{V}$ Data Out Open $T_A = 25^\circ\text{C}$
$I_{CC2}$	Power supply current			70	$\text{mA}$	All inputs = $5.25\text{V}$ Data Out Open $T_A = 0^\circ\text{C}$
$V_{IL}$	Input "low" voltage	-0.5		+0.65	$\text{V}$	
$V_{IH}$	Input "high" voltage	2.2		$V_{CC}$	$\text{V}$	
$V_{OL}$	Output "low" voltage			+0.45	$\text{V}$	$I_{OL} = 1.9\text{mA}$
$V_{OH}$	Output "high" voltage	2.4			$\text{V}$	$I_{OH} = -100\mu\text{A}$
$C_{IN}$	Input capacitance		4	7	$\text{pF}$	$V_{IN} = 0\text{V}$
$C_{OUT}$	Output capacitance		7	10	$\text{pF}$	$V_{OUT} = 0\text{V}$

## NOTES:

- Stresses above those listed under "Maximum Guaranteed Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device of these or any other condition above those indicated in the operation sections of this specification is not implied.
- For operating at elevated temperatures the device must be derated based on a  $+150^\circ\text{C}$  maximum junction temperature and a thermal resistance of  $150^\circ\text{C/W}$  junction to ambient ("B" pkg.) ("I" pkg.,  $100^\circ\text{C/W}$ ).
- All inputs protected against static charge.
- Parameter valid over operating temperature range unless otherwise specified.
- All voltage measurements are referenced to ground.
- Manufacturer reserves the right to make design and process changes and improvements.
- Typical values are at  $+25^\circ\text{C}$  and nominal supply voltages.
- This specification valid for all devices manufactured after March 31, 1973.

## SIGNETICS MOS STANDARD ROM CODES

PART NUMBER	CODE NUMBER	DESCRIPTION
2513	CM2140	New ASCII Character Generator, Upper Case 7 x 5, Horizontal Scan
2513	CM3030	Old ASCII Character Generator, Upper Case, 7 x 5, Horizontal Scan
2513	CM4800	Katakana Character Generator, 7 x 5, Horizontal Scan
2513	CM2170	ASCII Character Generator, Upper Case with Yen Sign, 7 x 5, Horizontal Scan
2513	CM3021	ASCII Character Generator, Lower Case, 7 x 5, Horizontal Scan
2516	CM3001/3010	ASCII Character Generator, Upper Case, 10 x 7, Horizontal Scan (2 chips)
2516	CM3041	ASCII Character Generator, Lower Case, 10 x 7, Horizontal Scan
2516	CM2150	ASCII Character Generator, Upper Case, 5 x 7, Vertical Scan
2516	CM3970/3980	ASCII Character Generator, Upper Case, 12 x 8, Horizontal Scan (2 chips)
2526	CM3400	ASCII Character Generator with EBCDIC and BAUDOT code translations, Upper Case, 7 x 9, Vertical Scan
2526	CM3940	ASCII Character Generator, Upper Case, 7 x 9, Horizontal Scan
2526	CM6760	Katakana Character Generator, 7 x 9, Horizontal Scan
2530	CM3530	Code Converter, ASCII to EBCDIC and EBCDIC to ASCII
2580	CMXXXX	Random code pattern for evaluation purposes

**signetics**

D-MOS  
PRODUCT  
SPECIFICATIONS







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**D-MOS Functional Index**

**D-MOS**

<b>SD200/201</b>	<b>Field Effect Transistor N-Channel Enhancement</b>	<b>8-1</b>
<b>SD202/203</b>	<b>Field Effect Transistor N-Channel Enhancement</b>	<b>8-5</b>
<b>SD210/211</b>	<b>Field Effect Transistor N-Channel Enhancement Mode</b>	<b>8-10</b>
<b>SD300/301</b>	<b>Dual Gate D-MOS FET N-Channel Enhancement</b>	<b>8-14</b>
<b>SD304</b>	<b>Dual Gate D-MOS FET N-Channel Enhancement</b>	<b>8-19</b>





### DESCRIPTION

The Signetics D-MOS SD200, SD201 are silicon insulated-gate field effect transistors of the n-channel enhancement mode type. They are fabricated by a new principle which gives superior high frequency performance up to 2 GHz. A special diode is connected between the gate and body of the SD201 that bypasses any voltage transient lying outside the range of -0.3 volts to +15 volts. Thus the gate of the SD201 is protected against damage in all normal handling and operating situations. Both devices are general purpose transistors especially suited for amplifier designs in the UHF range (500 MHz to 1 GHz). They have extremely high transconductance (15,000  $\mu$ mhos typ.), very low input capacitance (2.0 pF typ.) and extremely low feedback capacitance (0.13 pF typ.). The devices are hermetically sealed in modified 4 lead TO-72 packages. The SD200, SD201 combine high gain with low levels of noise, intermodulation and feedback capacitance. These parameters make them ideally suited for critical amplifier applications.

### FEATURES

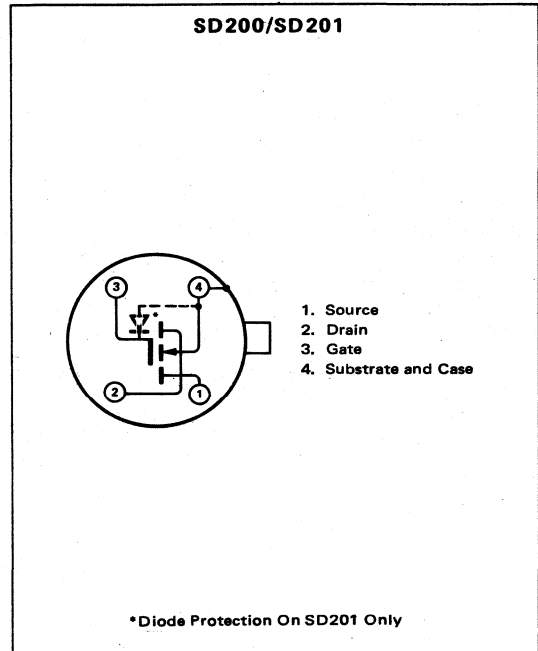
- HIGH GAIN THROUGH UHF RANGE (10 dB TYP. AT 1 GHz)
- ION IMPLANTED FOR GREATER CONTROL AND RELIABILITY
- LOW NOISE THROUGH UHF RANGE (4.5 dB TYP. AT 1 GHz)
- LOW INPUT CAPACITANCE (2.0 pF TYP.)
- LOW FEEDBACK CAPACITANCE (0.13 pF TYP.)
- HIGH DRAIN-TO-SOURCE VOLTAGE (+30V TYP.)
- HIGH FORWARD TRANSCONDUCTANCE (15,000  $\mu$ MHOS TYP.)
- WIDE DYNAMIC RANGE
- POSITIVE BIAS ONLY

### ABSOLUTE MAXIMUM RATINGS

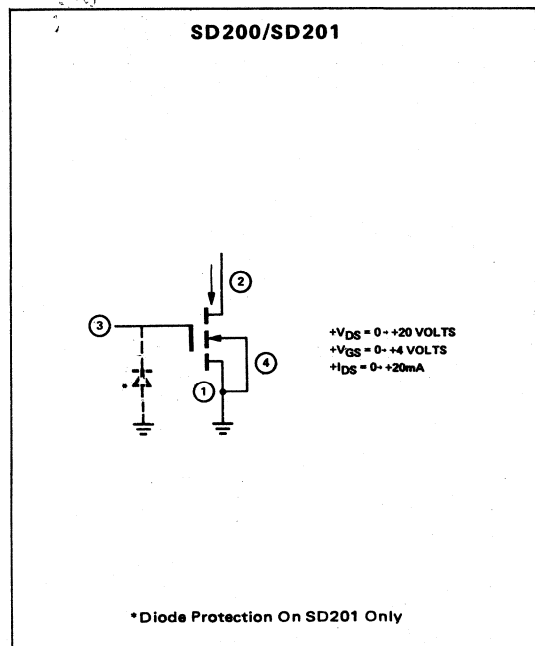
( $T_A = 25^\circ\text{C}$  Unless Otherwise Specified)

Drain-to-Source Voltage ( $V_{DS}$ )	+25V
Drain-to-Substrate Voltage ( $V_{DB}$ )	+25, -0.3V
Source-to-Substrate Voltage ( $V_{SB}$ )	+14, -0.3V
DC Gate-to-Source Voltage ( $V_{GS}$ )	
SD200	$\pm 40$ V
SD201	-0.3, +15V
Drain Current ( $I_D$ )	50 mA
Ambient Temperature Range	
Storage	-65°C to 175°C
Operating	-65°C to 125°C
Transistor Dissipation ( $P_T$ )	
At 25°C Case Temperature	300 mW
Temperature Above 25°C	derate at 2mW/°C

### PIN CONFIGURATION (Bottom Views)



### COMMON SOURCE BIAS SCHEME

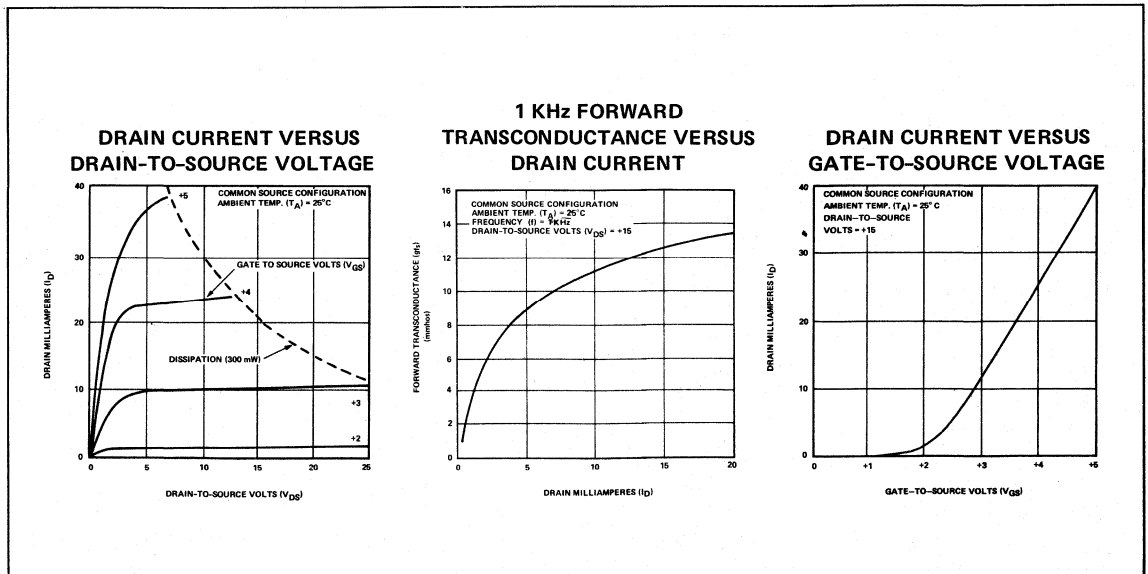


# SIGNETICS D-MOS FIELD EFFECT TRANSISTOR ■ SD200/201

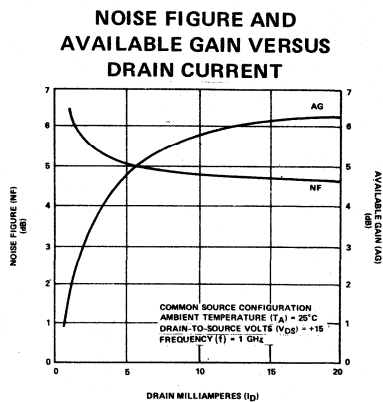
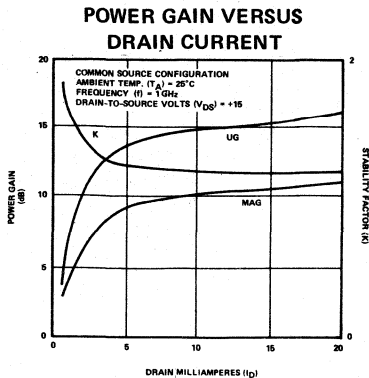
## ELECTRICAL CHARACTERISTICS SD200, SD201 AT $T_A = 25^\circ\text{C}$

CHARACTERISTIC	SYMBOL	CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
Drain to Source Breakdown Voltage	$BV_{DS}$	$V_{GS} = 0V, I_D < 1\mu A$	+25	+30		V
Gate Leakage Current	$I_{GSS}$	SD200 $V_{GS} = \pm 10V, V_{DS} = 0V$			0.1	nA
		SD201 $V_{GS} = +10V, V_{DS} = 0V$		0.001	1.0	$\mu A$
Drain to Source Current	$I_D$ (off)	$V_{DS} = 15V, V_{GS} = 0V$		0.001	1.0	$\mu A$
Zero Bias Drain Current	$I_{DSS}$					
Threshold Voltage	$V_T$	$V_{DS} = V_{GS} = V_T, I_D = 1\mu A$	+0.5	+1.0	+2.5	V
Forward Transconductance	$g_{fs}$	$V_{DS} = 15V, V_{GS} \cong 4V, I_D = 20\text{ mA}, f = 1\text{ KHz}$	13.0	15.0		mmhos
Small Signal Short Circuit Capacitances						
Input	$C_{iss}$	$V_{DS} = 15V, I_D = 20\text{ mA}, f = 1\text{ MHz}$		2.0	2.6	pF
Output	$C_{oss}$		1.0	1.2		
Reverse Transfer	$C_{rss}$		0.13	0.30		
Power Gain	$G_{pS}$	$V_{DS} = 15V, V_{GS} \cong 4V$	8	10		dB
Noise Figure	NF	$I_D = 20\text{ mA}, f = 1\text{ GHz}$		4.5	6.0	dB
Drain to Source on Resistance	$r_{DS(on)}$	$V_{GS} = 5V, I_D = 0.1\text{ mA}$		40	70	ohms
Intercept Point	$P_i$	$V_{DS} = 15V, I_D = 20\text{ mA}, f = 1\text{ GHz}, \Delta f = 2\text{ MHz}$		29		dBm

## CHARACTERISTIC CURVES

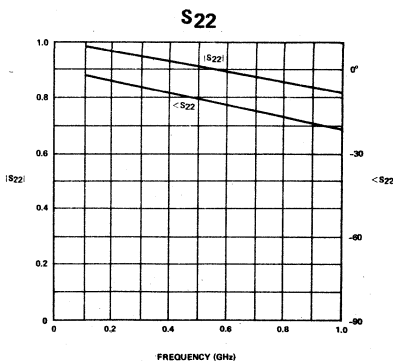
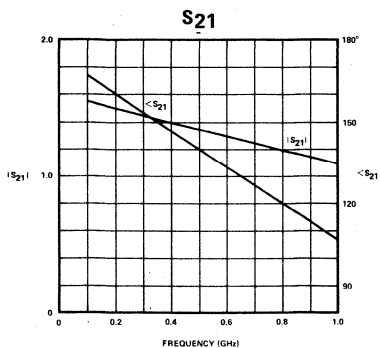
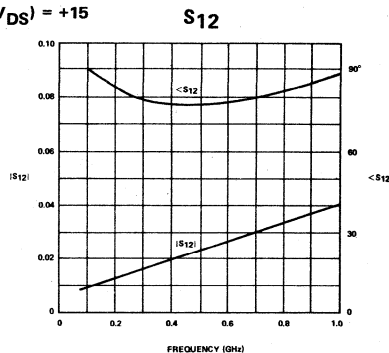
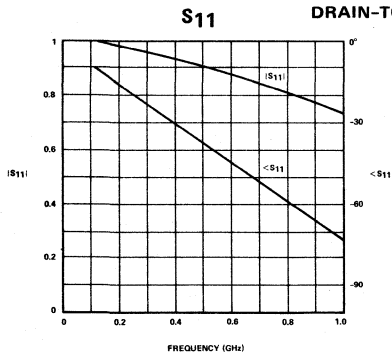


CHARACTERISTIC CURVES (Cont'd.)

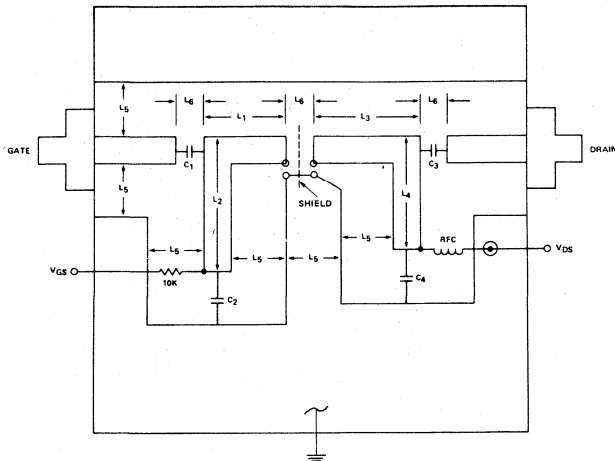


“S” PARAMETERS

COMMON SOURCE CONFIGURATION  
 AMBIENT TEMPERATURE ( $T_A$ ) = 25°C  
 DRAIN MILLIAMPERES ( $I_D$ ) = 20  
 DRAIN-TO-SOURCE VOLTS ( $V_{DS}$ ) = +15



1 GHz NOISE FIGURE AND POWER GAIN TEST FIXTURE



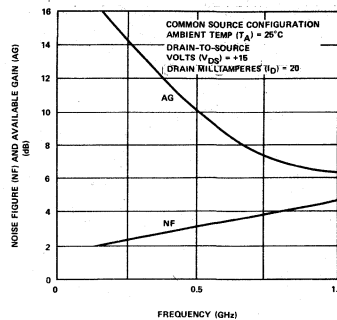
Dielectric is 1/16" teflon-fiberglass (3M-K6098-11)

All microstrip width = 0.175 inch

- |                     |                               |
|---------------------|-------------------------------|
| $L_1 = 0.48$ inch   | $C_1 = C_2 = C_3 = 0.8-10$ pF |
| $L_2 = 1.52$ inches | Johanson 5201                 |
| $L_3 = 0.64$ inch   | $C_4 = 1-20$ pF               |
| $L_4 = 1.36$ inches | Johanson 5501                 |
| $L_5 = 5/16$ inch   | RFC = 10 turns 1/4" Diam      |
| $L_6 = 1/8$ inch    | 26 AWG                        |
|                     | 1000pF bypass                 |
|                     | Cory FT4-01-2                 |
|                     | Launchers are OSM248-2        |

Note: Shield and 4 tunable capacitors on ground plane side of amplifier.

OPTIMUM NOISE FIGURE AND AVAILABLE GAIN VERSUS FREQUENCY



#### DESCRIPTION

The Signetics D-MOS SD202, SD203 are silicon insulated-gate field effect transistors of the n-channel enhancement mode type. They are fabricated by a new principle which gives superior high frequency performance up to 2 GHz. A special diode is connected between the gate and body of the SD203 that bypasses any voltage transient lying outside the range of -0.3 volts to +10 volts. Thus the gate of the SD203 is protected against damage in all normal handling and operating situations. Both devices are general purpose transistors especially suited for amplifier designs in the UHF range (500 MHz to 2 GHz). They have extremely high transconductance (20,000  $\mu$ mhos typ.), very low input capacitance (3.0 pF typ.) and extremely low feedback capacitance (0.20 pF typ.). The devices are hermetically sealed in modified 4 lead TO-72 packages. The SD202, SD203 combine high gain with low levels of noise, intermodulation and feedback capacitance. These parameters make them ideally suited for critical amplifier applications.

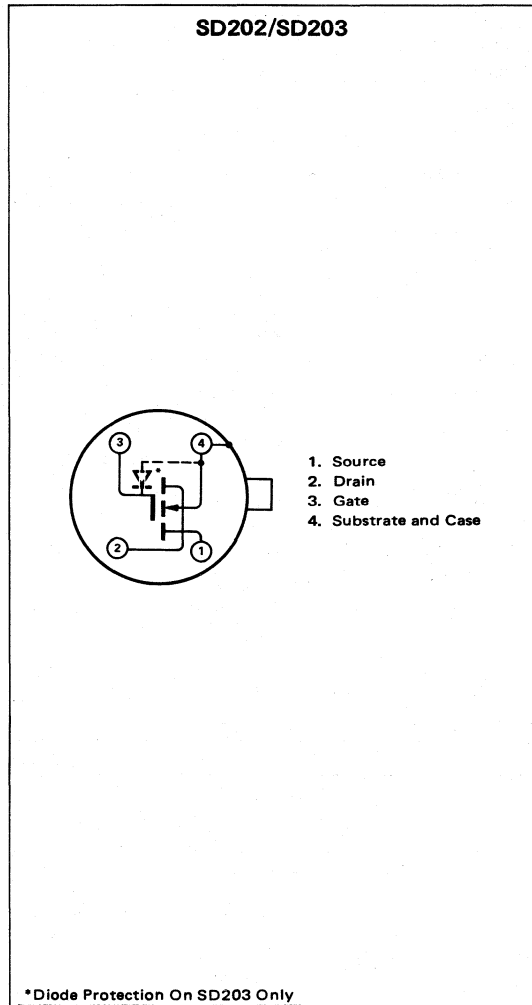
#### FEATURES

- HIGH GAIN THROUGH UHF RANGE (10 dB TYP. AT 1.5 GHz)
- ION IMPLANTED FOR GREATER CONTROL AND RELIABILITY
- LOW NOISE THROUGH UHF RANGE (3.2 dB TYP. AT 1.0 GHz)
- LOW INPUT CAPACITANCE (3.0 pF TYP.)
- LOW FEEDBACK CAPACITANCE (0.20 pF TYP.)
- HIGH DRAIN-TO-SOURCE VOLTAGE (+25V TYP.)
- HIGH FORWARD TRANSCONDUCTANCE (20,000  $\mu$ MHOS TYP.)
- WIDE DYNAMIC RANGE
- POSITIVE BIAS ONLY

#### ABSOLUTE MAXIMUM RATINGS

Drain-to-Source Voltage ( $V_{DS}$ )	+20V
Drain-to-Substrate Voltage ( $V_{DB}$ )	+20V, -0.3V
Source-to-Substrate Voltage ( $V_{SB}$ )	+14V, -0.3V
DC Gate-to-Source Voltage ( $V_{GS}$ )	
SD202	±40V
SD203	-0.3V, +10V

#### PIN CONFIGURATION (Bottom Views)



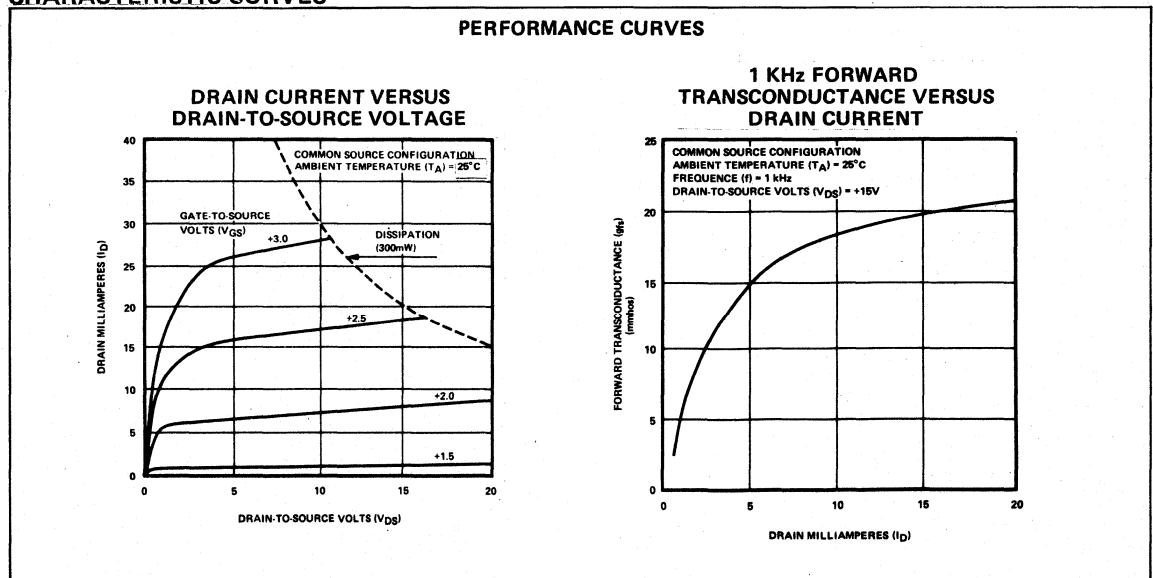
Drain Current ( $I_D$ )	50mA
Ambient Temperature Range	
Storage	-65°C to 175°C
Operating	-65°C to 125°C
Transistor Dissipation ( $P_T$ )	
At 25°C Case Temperature	300mW
Temperature Above 25°C	derate at 2mW/°C

ELECTRICAL CHARACTERISTICS SD202, SD203 AT  $T_A = 25^\circ\text{C}$

CHARACTERISTIC	SYMBOL	CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
Drain to Source Breakdown Voltage	$BV_{DS}$	$V_{GS} = 0V, I_D < 1\mu A$	+20	+25		V
Gate Leakage Current	$I_{GSS}$	SD202 $V_{GS} = \pm 10V, V_{DS} = 0V$			0.1	nA
		SD203 $V_{GS} = +10V, V_{DS} = 0V$		0.001	1.0	$\mu A$
Drain to Source Current	$I_{D(off)}$	$V_{DS} = +15V, V_{GS} = 0V$		0.001	1.0	$\mu A$
Zero Bias Drain Current	$I_{DSS}$					
Threshold Voltage	$V_T$	$V_{DS} = V_{GS} = V_T, I_D = 1\mu A$	+0.1	+0.8	+2.0	V
Forward Transconductance	$g_{fs}$	$V_{DS} = +15V, V_{GS} \cong +2.5V, I_D = 20mA, f = 1\text{ kHz}$	18	20		mmhos
Small Signal Short Circuit Capacitances		$V_{DS} = +15V, I_D = 20mA, f = 1\text{ MHz}$				
Input	$C_{iss}$			3.0	3.5	
Output	$C_{oss}$			1.0	1.2	pF
Reverse Transfer	$C_{rss}$			0.20	0.35	
Power Gain*	$G_{PS}$	$V_{DS} = +15V, V_{GS} \cong +2.5V, I_D = 20mA, f = 1.0\text{ GHz}$	8	10		dB
Noise Figure*	NF			3.2	4.5	dB
Power Gain*	$G_{PS}$	$V_{DS} = +15V, V_{GS} \cong +2.5V, I_D = 20mA, f = 1.8\text{ GHz}$	4	6		dB
Noise Figure*	NF			5.0	6.0	dB
Drain to Source on Resistance	$r_{DS(on)}$	$V_{GS} = +15V, I_D = 0.1mA$		35	50	ohms
Intercept Point	$P_i$	$V_{DS} = +15V, I_D = 20mA, f = 1\text{ GHz}, \Delta f = 2\text{ MHz}$		29		dBm

\*Measured In Amplifier Test Fixture

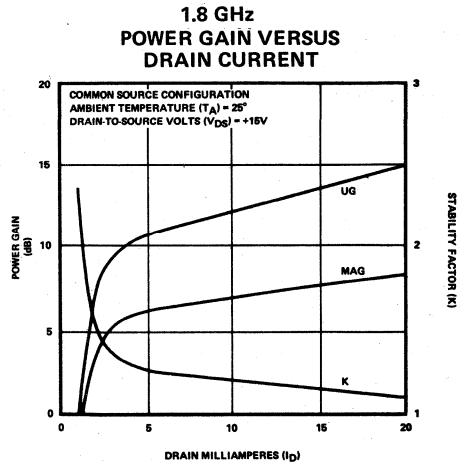
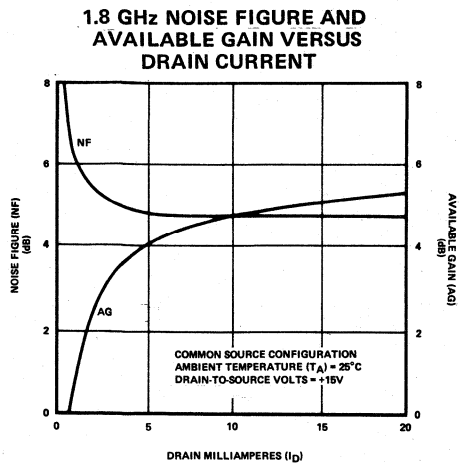
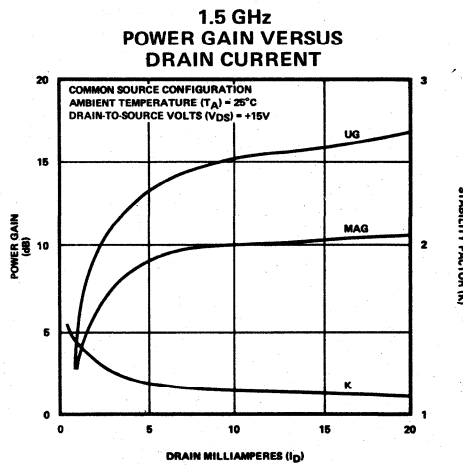
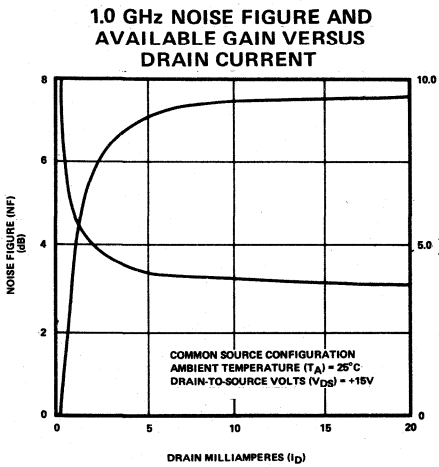
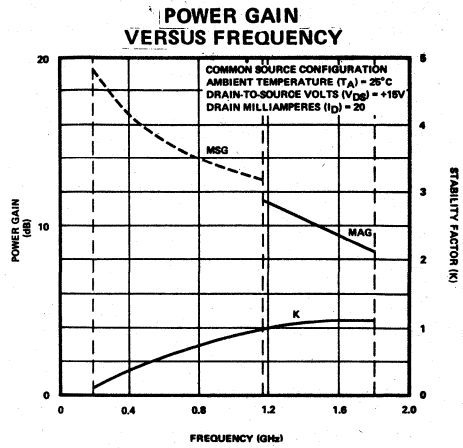
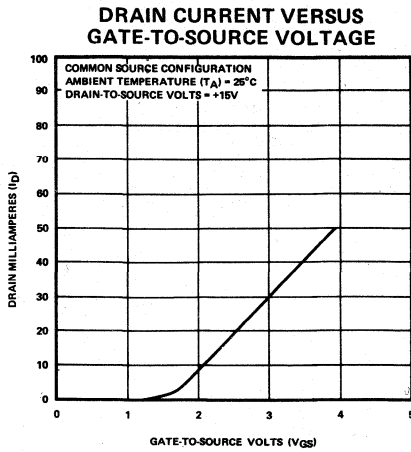
CHARACTERISTIC CURVES





CHARACTERISTIC CURVES (Cont'd)

PERFORMANCE CURVES (Cont'd)

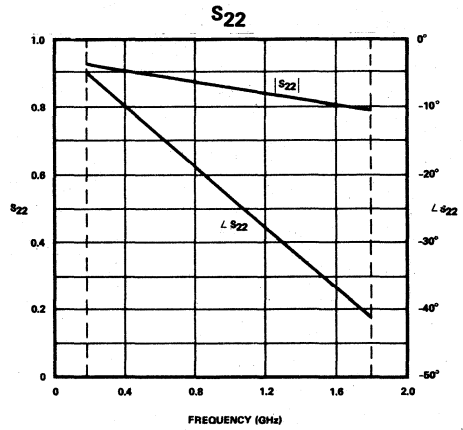
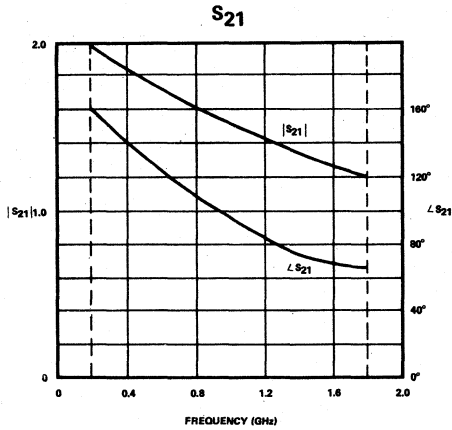
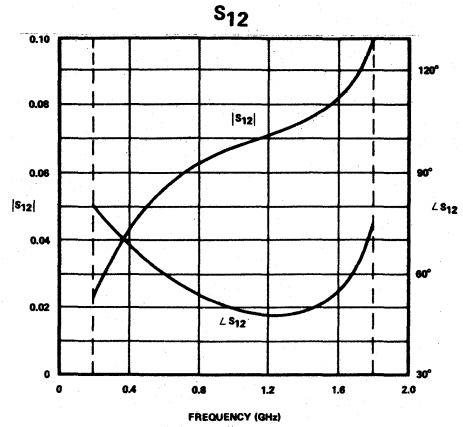
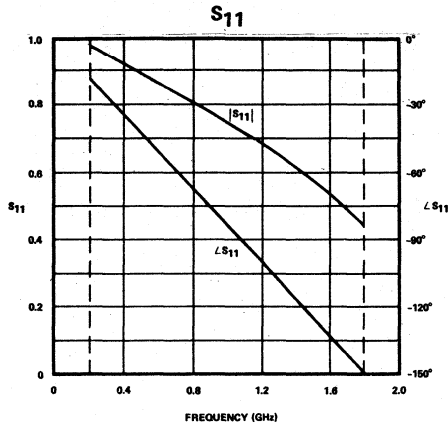


CHARACTERISTIC CURVES (Cont'd)

"S" PARAMETERS

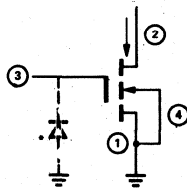
COMMON SOURCE CONFIGURATION  
 AMBIENT TEMPERATURE ( $T_A$ ) = 25°C

DRAIN MILLIAMPERES ( $I_D$ ) = 20  
 DRAIN-TO-SOURCE VOLTS ( $V_{DS}$ ) = +15



COMMON SOURCE BIAS SCHEME

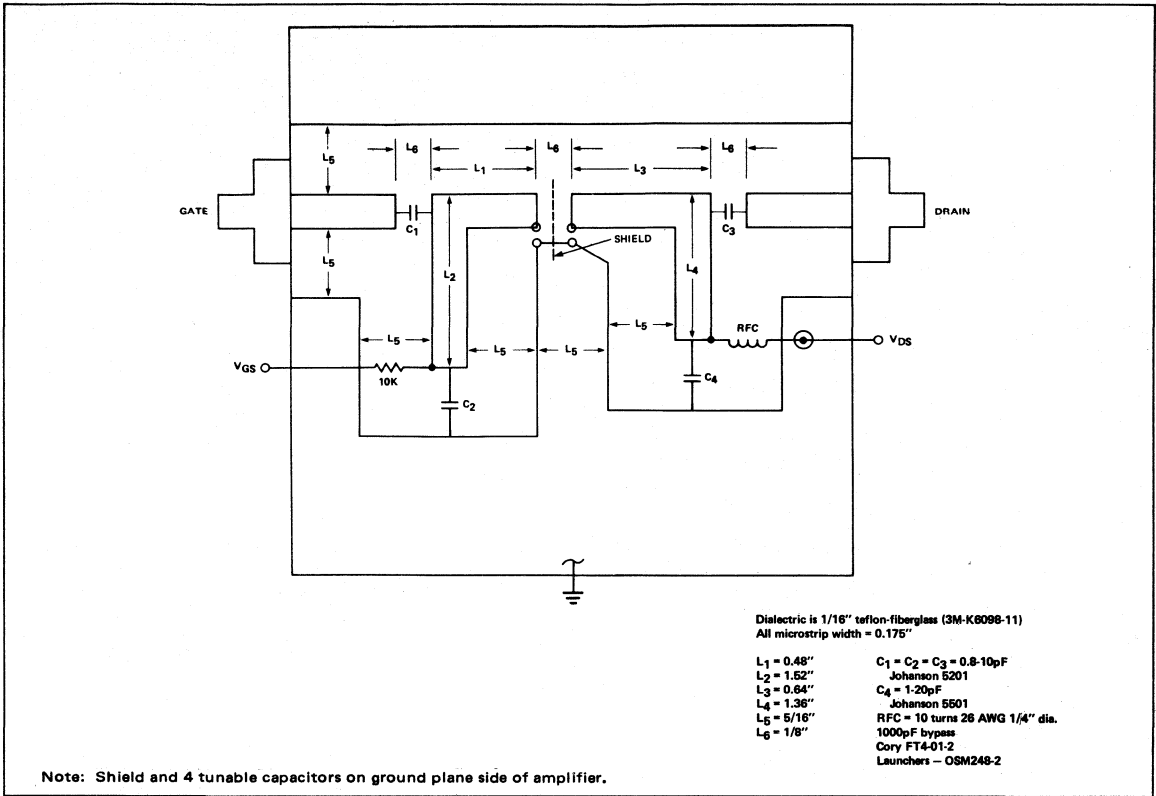
SD202/203



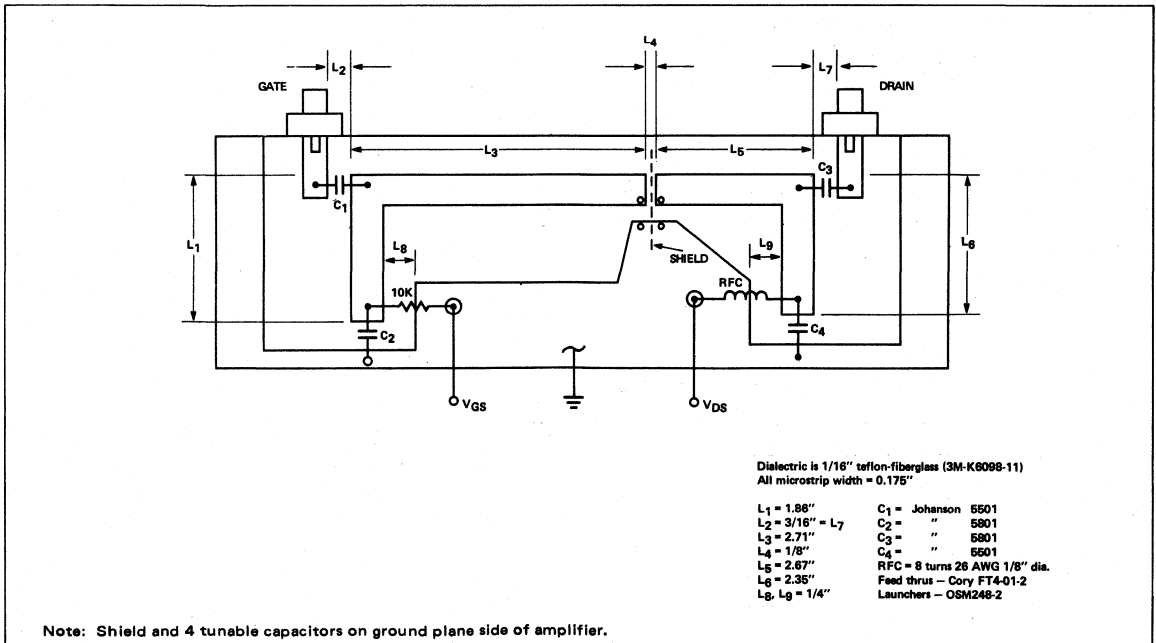
+ $V_{DS}$  = 0 - +20 VOLTS  
 + $V_{GS}$  = 0 - +4 VOLTS  
 + $I_{DS}$  = 0 - +20mA

\*Diode Protection On SD203 Only

1 GHz NOISE FIGURE AND POWER GAIN TEST FIXTURE



1.8 GHz NOISE FIGURE AND POWER GAIN TEST FIXTURE



#### DESCRIPTION

The Signetics D-MOS SD210, SD211 are silicon insulated-gate field effect transistors of the n-channel enhancement mode type. They are fabricated by a new principle which gives high switching speed and low capacitance. A special diode is connected between the gate and body of the SD211 that bypasses any voltage transient. Thus the gate of the SD211 is protected against damage in all normal handling and operating situations. The SD210 is intended to switch signals up to  $\pm 10V$ , and the SD211 is a  $\pm 5V$  switch. Both devices feature low on resistance ( $30\Omega$  typ.), very low output capacitance (1.3 pF typ.) and extremely low feedback capacitance (0.2 pF typ.). The devices are hermetically sealed in 4 lead TO-72 packages.

#### FEATURES

- ION IMPLANTED FOR GREATER RELIABILITY
- 600-ps TYPICAL PROPAGATION DELAY TIME
- LOW ON RESISTANCE ( $30\Omega$  TYP)
- HIGH DRAIN-TO-SOURCE VOLTAGE (25V TYP)
- LOW FEEDBACK CAPACITANCE (0.2 pF TYP)
- LOW OUTPUT CAPACITANCE (1.3 pF TYP)
- LOW FEED THROUGH TRANSIENT

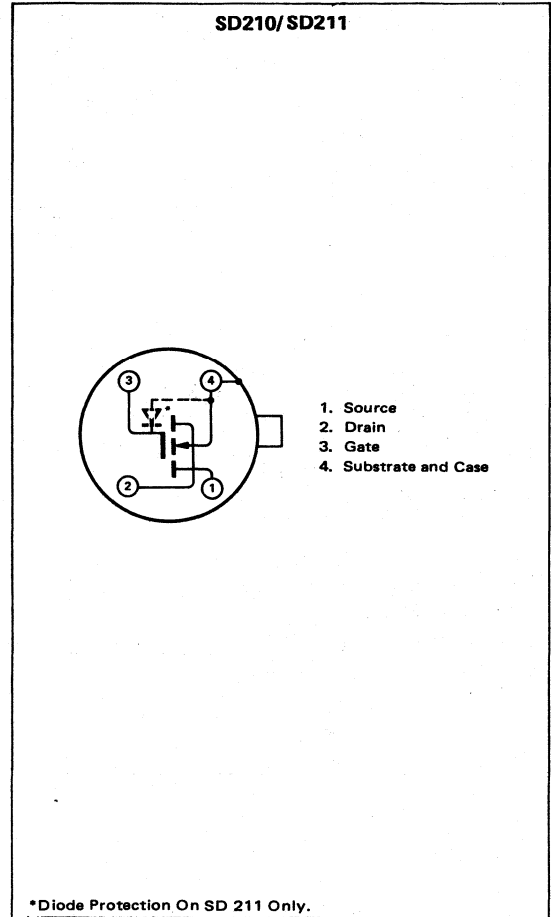
#### APPLICATIONS

ANALOG SWITCH

MULTIPLEXERS

DIGITAL SWITCH

#### PIN CONFIGURATION (Bottom Views)



#### ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ C$ Unless Otherwise Specified

Leakage Current = $10\mu A$ .	SD210	SD211
Drain-to-Source ( $V_{DS}$ )	27	20
Source-to-Drain ( $V_{SD}$ )	11	6
Drain-to-Substrate ( $V_{DB}$ )	30	25
Source-to-Substrate ( $V_{SB}$ )	12*	12
Gate-to-Source ( $V_{GS}$ )	30	15
Gate-to-Substrate ( $V_{GB}$ )	30	17
Gate-to-Drain ( $V_{GD}$ )	30	15

Drain Current ( $I_D$ )	50mA
Ambient Temperature Range	
Storage	$-65^\circ C$ to $175^\circ C$
Operating	$-65^\circ C$ to $125^\circ C$
Transistor Dissipation ( $P_T$ )	
At $25^\circ C$ Case Temperature	300 mW
Temperature Above $25^\circ C$	derate at $2mW/^\circ C$

\*See Application note.

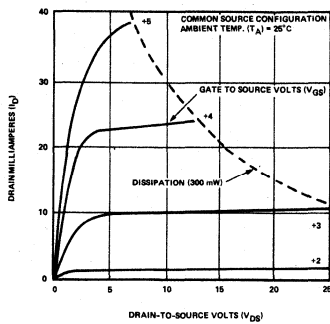
ELECTRICAL CHARACTERISTICS SD210, SD211 AT  $T_A = 25^\circ\text{C}$

CHARACTERISTIC	SYMBOL	CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
Drain to Source Breakdown Voltage	$BV_{DS}$	$V_{GS} = 0V, I_D = 10nA$ $V_{SB} = -2V$	SD 210	15	25	V
			SD 211	15	25	
Source to Drain Breakdown Voltage	$BV_{SD}$	$V_{GS} = 0V, I_D = 10nA$ $V_{DB} = -2V$	SD 210	11	14	V
			SD 211	6	8	
Gate Leakage Current	$I_{GSS}$	SD 210 $V_{GS} = \pm 10V, V_{DS} = 0V$			0.1	nA
		SD 211 $V_{GS} = +10V, V_{DS} = 0V$		1	10	nA
Drain to Source Current	$I_D$ (off)	$V_{DS} = 10V, V_{GS} = 0V$		1	10	nA
Zero Bias Drain Current	$I_{DSS}$					
Threshold Voltage	$V_T$	$V_{DS} = V_{GS} = V_T, I_D = 1\mu A, V_{SB} = 0$	+0.5	+1.0	+2.5	V
Forward Transconductance	$g_{fs}$	$V_{DS} = 15V, V_{GS} \cong 4V,$ $I_D = 20mA, f = 1\text{ kHz}$	13.0	15.0		mmhos
Small Signal Short Circuit Capacitances						
Input	$C_{iss}$	$V_{DS} = 10V, f = 1\text{ MHz}$		2.6	3.0	pF
Output	$C_{oss}$			1.3	1.5	
Reverse Transfer	$C_{rss}$			0.20	0.30	
Drain to Source on Resistance	$r_{DS(on)}$	$V_{GS} = 10V, I_D = 0.1mA, V_{SB} = 0$		30	45	ohms

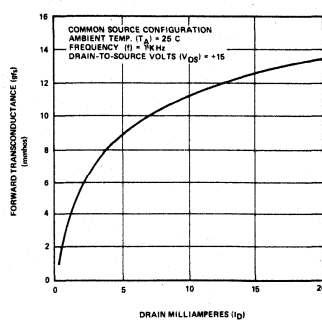
CHARACTERISTIC CURVES

PERFORMANCE CURVES

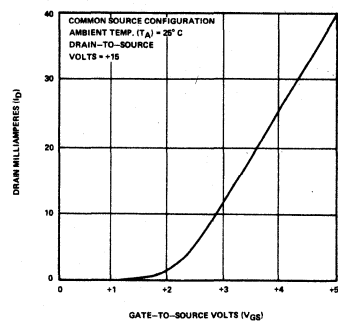
DRAIN CURRENT VERSUS DRAIN-TO-SOURCE VOLTAGE



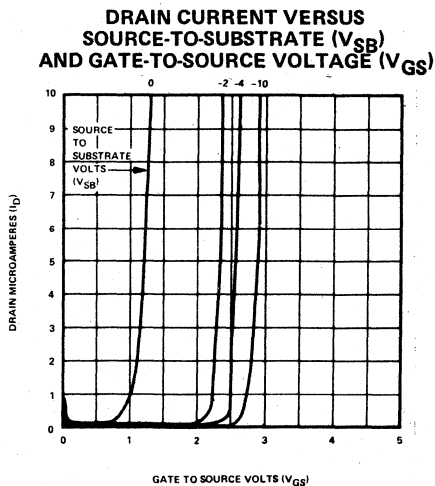
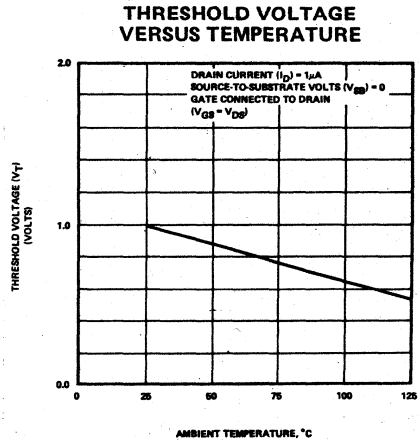
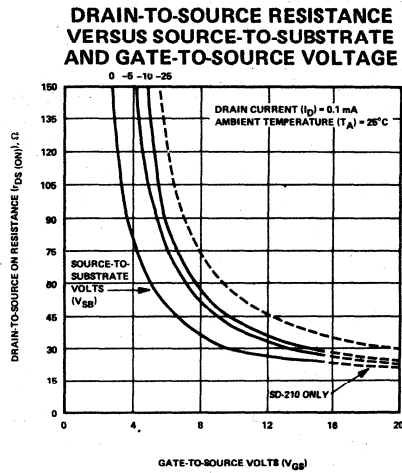
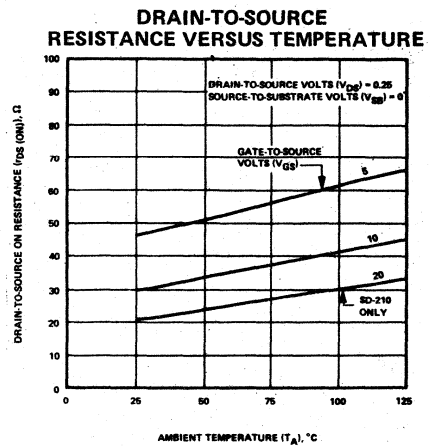
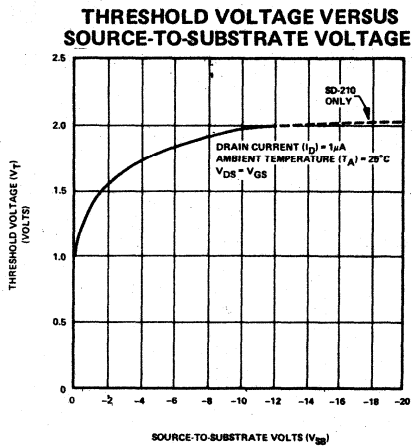
1 KHz FORWARD TRANSCONDUCTANCE VERSUS DRAIN CURRENT



DRAIN CURRENT VERSUS GATE-TO-SOURCE VOLTAGE

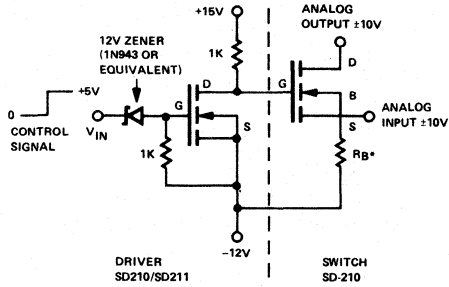


CHARACTERISTIC CURVES (Cont'd)



APPLICATION NOTE

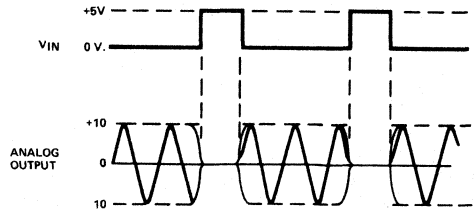
SD-210 used as ± 10V switch



\*R<sub>B</sub> is selected to limit source to substrate leakage.

$$I_{SB}(\text{max}) = \frac{V_{SB}(\text{max}) - 12V}{R_B}$$

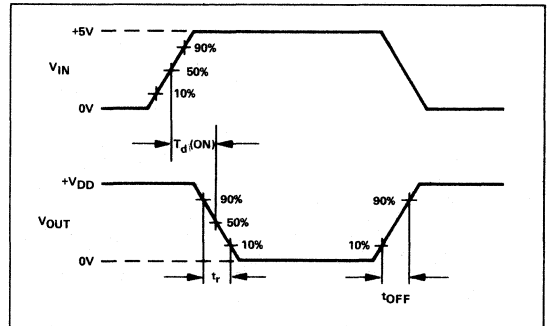
TYPICAL WAVEFORMS



SWITCHING CHARACTERISTICS

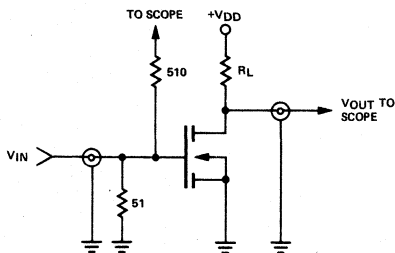
VDD	R <sub>L</sub>	t <sub>d</sub> (ON)(ns)		t <sub>r</sub> (ns)		t <sub>OFF</sub> (ns)	
		TYP	MAX	TYP	MAX	TYP	MAX
5	680	0.6	1.0	0.7	1.0	9.0	*
10	680	0.7		0.8		9.0	
15	1K	0.9		1.0		14.0	

SWITCHING WAVEFORMS



\*t<sub>OFF</sub> is dependent on R<sub>L</sub> and C<sub>L</sub> and does not depend on the device characteristics

TEST CIRCUIT



INPUT PULSE  
 t<sub>r</sub>, t<sub>f</sub> < 1ns  
 PULSE WIDTH = 100 ns  
 REP RATE = 1 MHz  
 SAMPLING SCOPE  
 t<sub>s</sub> < 350 ps  
 R<sub>IN</sub> = 1 MΩ  
 C<sub>IN</sub> = 2.0 pF

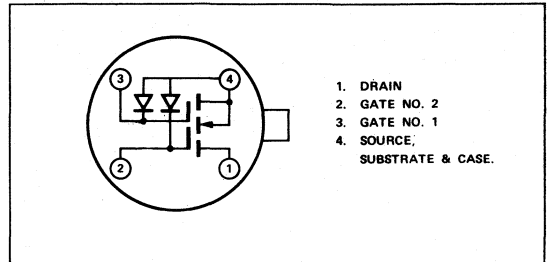
### DESCRIPTION

The Signetics D-MOS SD300 and SD301 are dual gate silicon insulated field effect transistors of the N-channel enhancement mode type. They are fabricated by a new principle which gives superior high frequency performance up to 2 GHz. Special diodes are connected between the two gates and the source. These diodes bypass any voltage transients which lie outside the range of  $-0.3$  volts to  $+25.0$  volts. Thus, the gates are protected against damage in all normal handling and operating situations. The device attributes make them ideally suited for a variety of high frequency amplifier and mixer applications. The presence of two gates plus the incorporation of the drift region in the structure, has allowed us to reduce feedback capacity,  $C_{rss}$  to  $0.02$  pF typ. A wide AGC capability plus a significant reduction in cross modulation is now available because of the inherent linearity of the devices. The SD300 and SD301 are hermetically sealed in a modified 4 lead TO-72 package.

### FEATURES

- LOWER CROSS-MODULATION AND WIDER DYNAMIC RANGE THAN BIPOLAR OR SINGLE GATE FETs.
- REVERSE AGC CAPABILITY.
- LINEAR MIXING CAPABILITY.
- DIODE PROTECTED GATES.
- HIGH FORWARD TRANSCONDUCTANCE  $g_{fs} = 10,000 \mu\text{mhos}$  (typ.).
- HIGH GAIN THROUGH UHF RANGE (13 dB typ. AT 1 GHz).
- LOW NOISE THROUGH UHF RANGE (6 dB typ. FOR SD301 AT 1 GHz).
- LOW INPUT CAPACITANCE (2.0 pF typ.).
- LOW FEEDBACK CAPACITANCE (0.02 pF typ.).
- LOW OUTPUT CAPACITANCE (0.6 pF typ. FOR SD301).
- ION IMPLANTED.
- POSITIVE BIAS ONLY.

### PIN CONFIGURATION (Bottom View)

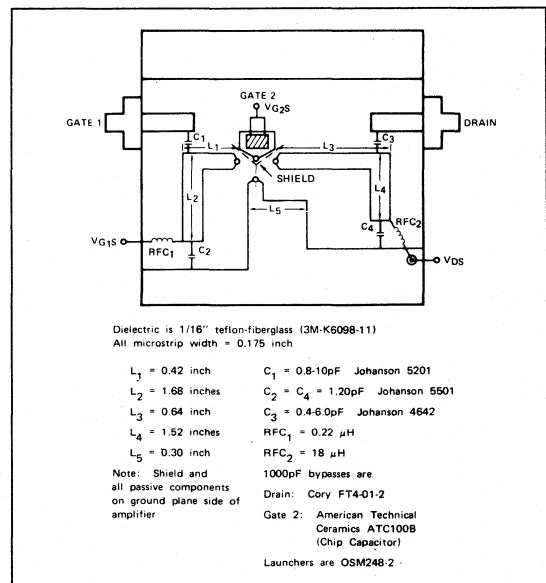


### ABSOLUTE MAXIMUM RATING

( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Drain-to-source voltage ( $V_{DS}$ )	+25V (max)
Gate No. 1-to-source voltage ( $V_{G1S}$ )	-0.3 to +15V dc
Gate No. 2-to-source voltage ( $V_{G2S}$ )	-0.3 to +25V dc
Drain current ( $I_D$ )	50 mA (max)
Ambient temperature range ( $T_A$ )	
Storage	$-65^\circ\text{C}$ to $+175^\circ\text{C}$
Operating	$-65^\circ\text{C}$ to $+125^\circ\text{C}$
Transistor Dissipation ( $P_T$ )	
At $25^\circ\text{C}$ case temperature	300mW
Temperature above $25^\circ\text{C}$	derate at $2.0\text{mW}/^\circ\text{C}$

### TEST FIXTURE





## ELECTRICAL CHARACTERISTICS SD300, SD301 at 25°C

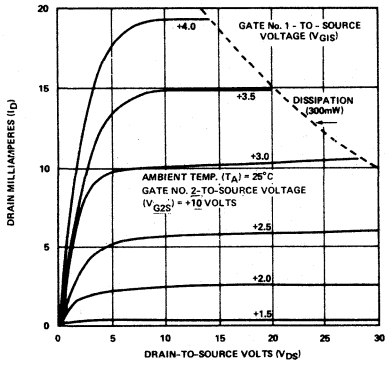
CHARACTERISTIC	SYMBOL	CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
Drain to Source Breakdown	$BV_{DS}$	$V_{G1S} = V_{G2S} = 0V, I_D = 5\mu A$	+25	+30		volts
Gate 1 Leakage Current	$I_{G1SS}$	$V_{G1S} = +5V, V_{G2S} = V_D = 0V$		0.001	0.1	$\mu A$
Gate 2 Leakage Current	$I_{G2SS}$	$V_{G2S} = 10V, V_{G1S} = V_D = 0V$		0.001	0.1	$\mu A$
Drain to Source Leakage Current	$I_D$ (off)	$V_{DS} = +15V, V_{G1S} = V_{G2S} = 0V$		0.001	1.0	$\mu A$
Zero Bias Drain Current	$I_{DSS}$					
Gate 1 Threshold Voltage	$V_{T1}$	$V_{DS} = V_{G1S} = V_{T1}$ $V_{G2S} = +10V$ $I_D = 1\mu A$	+0.1	+0.5	+2.0	volts
Gate 2 Threshold Voltage	$V_{T2}$	$V_{DS} = V_{G2S} = V_{T2}$ $V_{G1S} = +4V$ $I_D = 1\mu A$	+0.1	+0.5	+2.0	volts
Small Signal Short Circuit Capacitances Gate 2 A.C. Grounded Input	$C_{iss}$	$V_{DS} = +15V, V_{G1S} = +4V,$ $V_{G2S} = +10V, I_D = 18mA$ $f = 1 MHz$		2.0	2.5	pF
Output	$C_{oss}$	$V_{DS} = +15V$ $V_{G2S} = +10V$ $f = 1 MHz$	SD300	1.0	1.2	
			SD301	0.6	0.8	
Reverse Transfer	$C_{rss}$	$V_{DS} = +15V, V_{G2S} = +10V,$ $f = 1 MHz$		0.02		
Forward Transconductance	$g_{fs}$	$V_{DS} = +15V, V_{G1S} = +4V$ $V_{G2S} = +10V, I_D = 18mA$	8.0	10.0		mmhos
Power Gain *	$G_{ps}$	$V_{DS} = +15V,$ $V_{G1S} = +4V,$ $V_{G2S} = +10V$ $I_D = 18mA$	SD300	9.0	13.0	dB
			SD301	10.0	14.0	
Noise Figure *	NF	$f = 1 GHz$	SD300	8.0	9.0	dB
			SD301	6.0	7.0	
Power Gain	$G_{ps}$	$V_{DS} = +15V,$ $V_{G1S} = +4V,$ $V_{G2S} = +10V,$ $I_D = 18mA$	SD300	22	24	dB
			SD301	22	25	
Noise Figure	NF	$f = 200 MHz$	SD300	3.0	4.0	dB
			SD301	2.0	3.0	
Interfering Signal Level at Gate for 1% Cross Modulation Distortion. Peak Voltage	$E_{int}$	$V_{DS} = V_{G2S} = +15V$ $I_D = 18mA$ Wanted Signal $f = 500 MHz$ Interfering Signal $f = 501 MHz$		200		mV
Range of Automatic Gain Control	AGC ( $V_{G2S}$ )	$V_{DS} = +15V, V_{G1S} = +4V$ $f = 500 MHz$		40		dB
Drain to Source on Resistance	$r_{DS}$ (on)	$V_{G1S} = +5V, V_{G2S} = +10V,$ $I_D = 0.1mA$		90	130	ohms

\* Measured in Amplifier Test Fixture

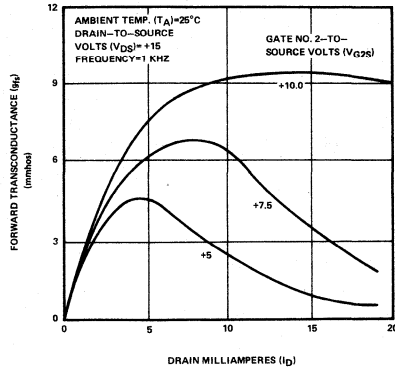
CHARACTERISTIC CURVES

PERFORMANCE CURVES

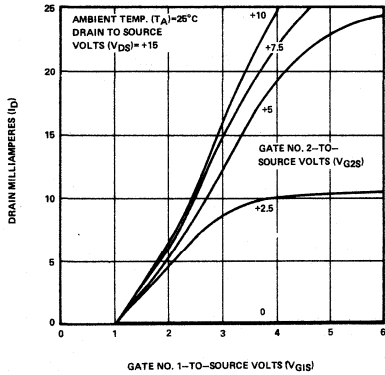
DRAIN CURRENT VERSUS DRAIN-TO-SOURCE VOLTAGE



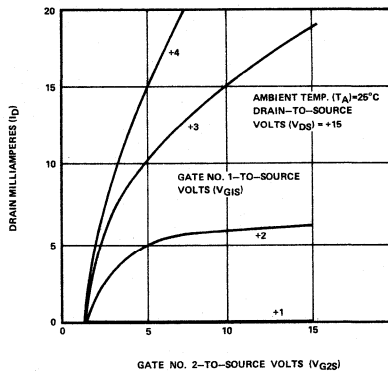
1 KHz FORWARD TRANSCONDUCTANCE VERSUS DRAIN CURRENT



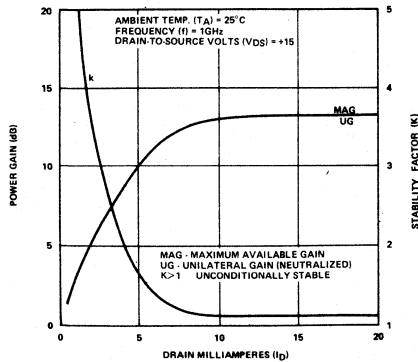
DRAIN CURRENT VERSUS GATE NO. 1-TO-SOURCE VOLTAGE



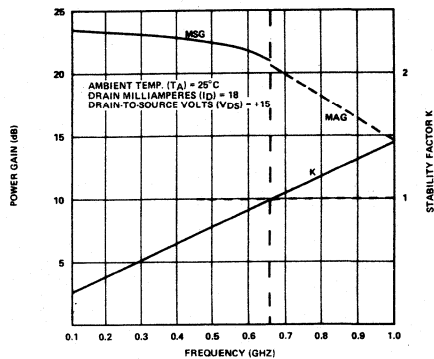
DRAIN CURRENT VERSUS GATE NO. 2-TO-SOURCE VOLTAGE



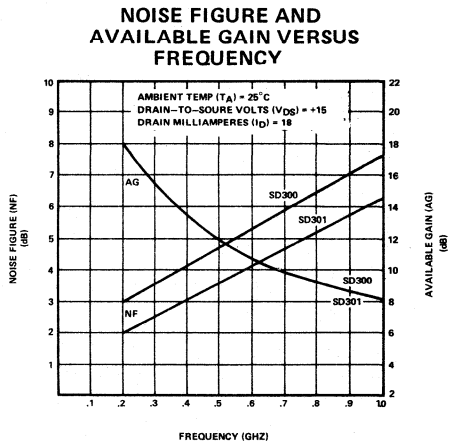
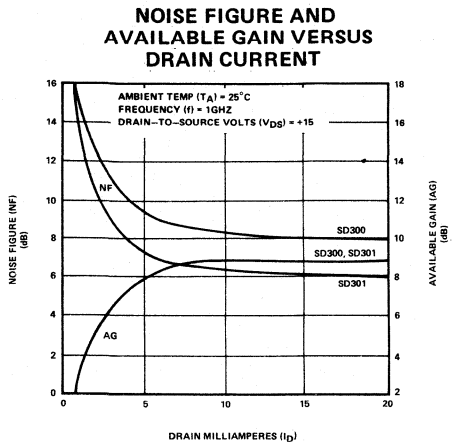
POWER GAIN VERSUS DRAIN CURRENT



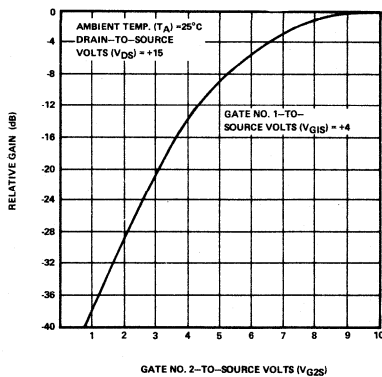
POWER GAIN VERSUS FREQUENCY



CHARACTERISTIC CURVES (Cont'd)

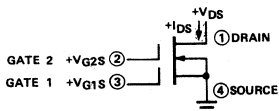


**AUTOMATIC GAIN CONTROL RANGE AT 500 MHZ**



DUAL GATE CASCODE BIAS SCHEME

SD 300/301

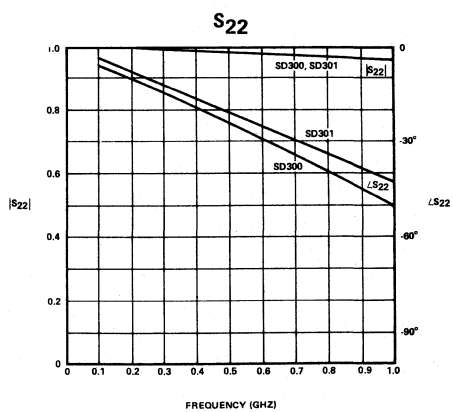
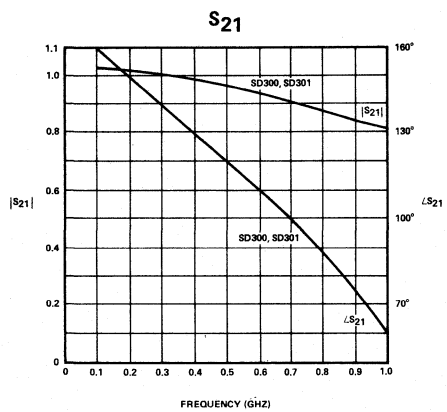
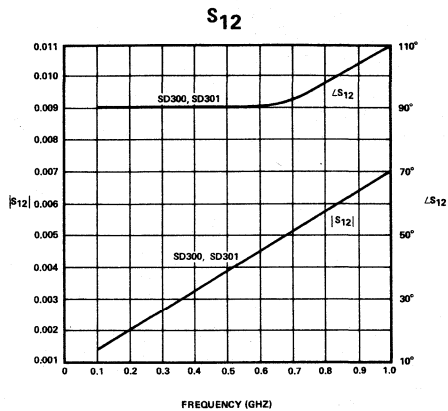
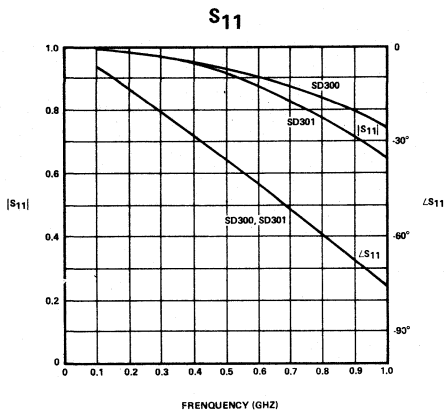


+ $V_{DS}$  = 0 - +20 VOLTS  
 + $V_{G1S}$  = 0 - +4 VOLTS  
 + $V_{G2S}$  = 0 - +10 VOLTS  
 + $I_{DS}$  = 0 - +20mA

CHARACTERISTIC CURVES

S PARAMETERS

AMBIENT TEMP. ( $T_A$ ) = 25°C  
 DRAIN MILLIAMPERES ( $I_D$ ) = 18  
 DRAIN-TO-SOURCE VOLTS ( $V_{DS}$ ) = +15



### VHF AND GENERAL PURPOSE RF APPLICATIONS

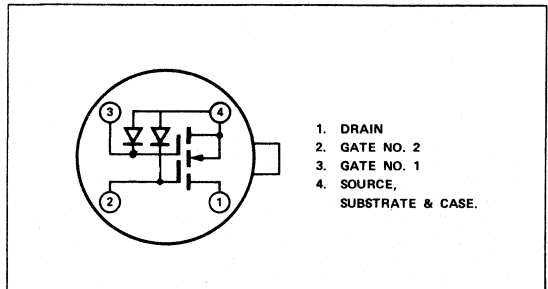
#### DESCRIPTION

The Signetics D-MOS SD304 is a dual gate silicon insulated field effect transistor of the N-channel enhancement mode type. It is fabricated by a new principle which gives superior high frequency performance up to 1 GHz. Special diodes are connected between the two gates and the source. These diodes bypass any voltage transients which lie outside the range of -0.3 volts to +25.0 volts. Thus, the gates are protected against damage in all normal handling and operating situations. The device attributes make it ideally suited for a variety of high frequency amplifier and mixer applications. The presence of two gates plus the incorporation of the drift region in the structure, has allowed us to reduce feedback capacity,  $C_{RSS}$  to 0.03 pF typ. A wide AGC capability plus a significant reduction in cross modulation is now available because of the inherent linearity of the devices. The SD304 is hermetically sealed in a modified 4 lead TO-72 package.

#### FEATURES

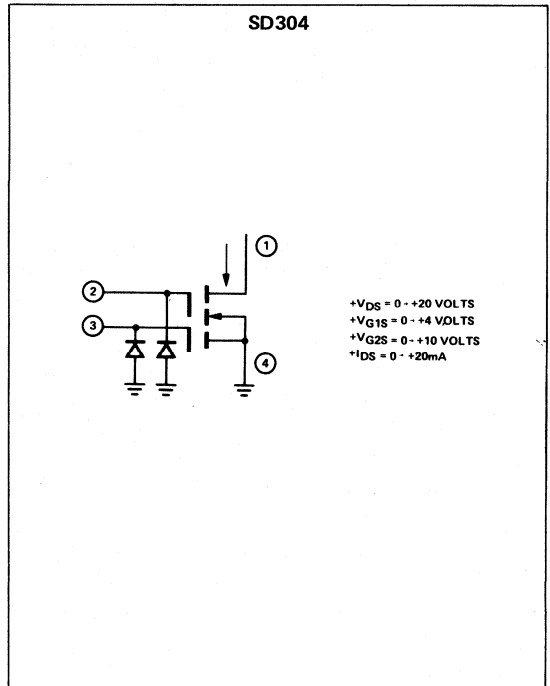
- LOWER CROSS-MODULATION AND WIDER DYNAMIC RANGE THAN BIPOLAR OR SINGLE GATE FETs.
- REVERSE AGC CAPABILITY.
- LINEAR MIXING CAPABILITY.
- DIODE PROTECTED GATES.
- HIGH FORWARD TRANSCONDUCTANCE  $g_{fs} = 10,000 \mu\text{mhos}$  (typ.).
- HIGH GAIN THROUGH VHF RANGE (16 dB typ. AT 500 MHz).
- LOW NOISE THROUGH VHF RANGE (5 dB typ. AT 500 MHz).
- LOW INPUT CAPACITANCE (2.4 pF typ.).
- LOW FEEDBACK CAPACITANCE (0.03 pF typ.).
- LOW OUTPUT CAPACITANCE (1.0 pF typ.).
- ION IMPLANTED.
- POSITIVE BIAS ONLY.

#### PIN CONFIGURATION (Bottom View)



1. DRAIN
2. GATE NO. 2
3. GATE NO. 1
4. SOURCE, SUBSTRATE & CASE.

#### DUAL GATE CASCODE BIAS SCHEME



- SD304
- + $V_{DS} = 0 - +20$  VOLTS
  - + $V_{G1S} = 0 - +4$  VOLTS
  - + $V_{G2S} = 0 - +10$  VOLTS
  - + $I_{DS} = 0 - +20$  mA

#### ABSOLUTE MAXIMUM RATING

( $T_A = 25^\circ\text{C}$  unless otherwise specified)

Drain-to-Source Voltage ( $V_{DS}$ )	+25V (max)
Gate No. 1-to-Source Voltage ( $V_{G1S}$ )	-0.3 to +10 Vdc
Gate No. 2-to-Source Voltage ( $V_{G2S}$ )	-0.3 to +15 Vdc
Drain Current ( $I_D$ )	30mA (max)

#### Ambient Temperature Range ( $T_A$ )

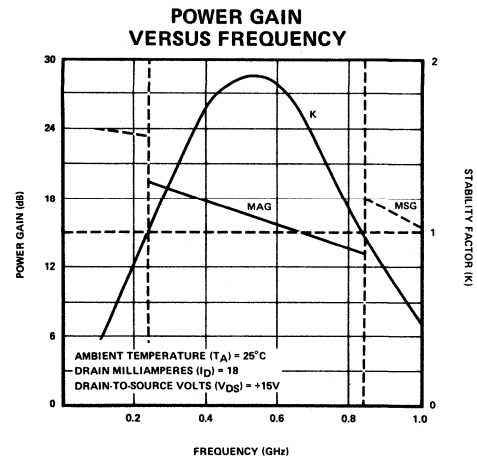
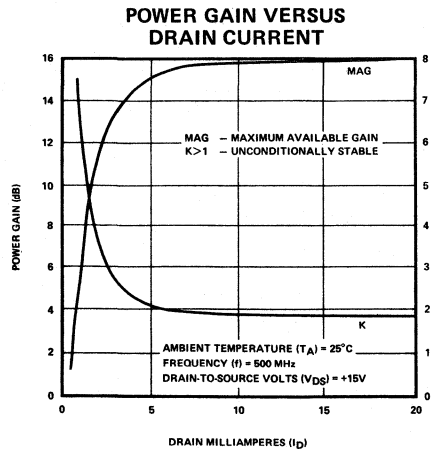
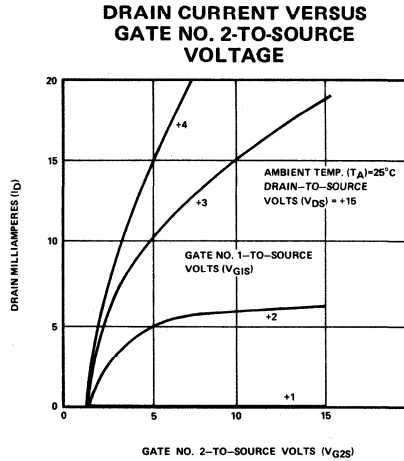
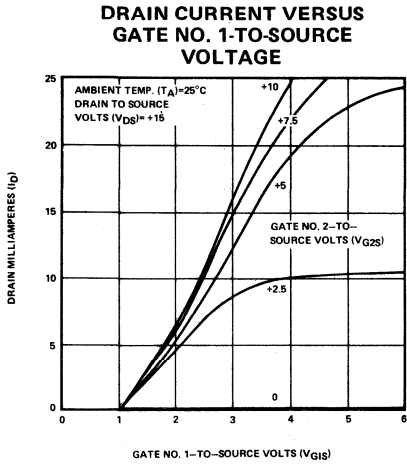
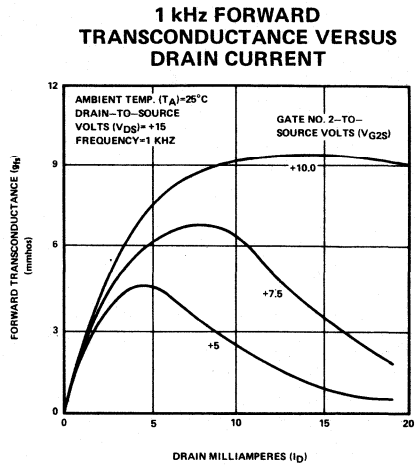
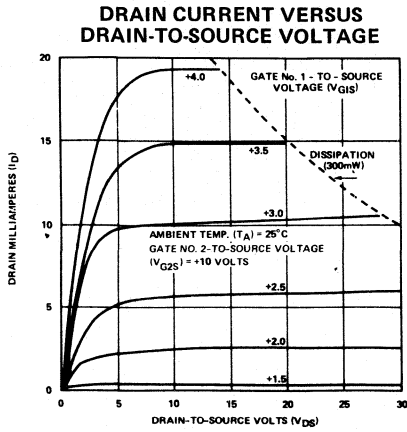
Operating	$-65^\circ\text{C}$ to $+125^\circ\text{C}$
Storage	$-65^\circ\text{C}$ to $+175^\circ\text{C}$
Transistor Dissipation ( $P_T$ )	
At $25^\circ\text{C}$ case temperature	300mW
Temperature above $25^\circ\text{C}$	derate at 2.0mW/ $^\circ\text{C}$

## ELECTRICAL CHARACTERISTICS SD304 at 25°C

CHARACTERISTIC	SYMBOL	CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
Drain to Source Breakdown	BV <sub>DS</sub>	V <sub>G1S</sub> = V <sub>G2S</sub> = 0V, I <sub>D</sub> = 1μA	+25	+30		volts
Gate 1 Leakage Current	I <sub>G1SS</sub>	V <sub>G1S</sub> = +5V, V <sub>G2S</sub> = V <sub>D</sub> = 0V		0.001	0.1	μA
Gate 2 Leakage Current	I <sub>G2SS</sub>	V <sub>G2S</sub> = +10V, V <sub>G1S</sub> = V <sub>D</sub> = 0V		0.001	0.1	μA
Drain to Source Leakage Current	I <sub>D</sub> (off)	V <sub>DS</sub> = +15V, V <sub>G1S</sub> = V <sub>G2S</sub> = 0V		0.001	1.0	μA
Zero Bias Drain Current	I <sub>DSS</sub>					
Gate 1 Threshold Voltage	V <sub>T1</sub>	V <sub>DS</sub> = V <sub>G1S</sub> = V <sub>T1</sub> V <sub>G2S</sub> = +10V I <sub>D</sub> = 1μA	+0.1	+0.5	+2.0	volts
Gate 2 Threshold Voltage	V <sub>T2</sub>	V <sub>DS</sub> = V <sub>G2S</sub> = V <sub>T2</sub> V <sub>G1S</sub> = +4V I <sub>D</sub> = 1μA	+0.1	+0.5	+2.0	volts
Small Signal Short Circuit Capacitances						
Input	C <sub>iss</sub>	V <sub>DS</sub> = +15V, V <sub>G1S</sub> = +4V, V <sub>G2S</sub> = +10V, I <sub>D</sub> = 18mA f = 1 MHz		2.4	2.6	pF
Output	C <sub>oss</sub>	V <sub>DS</sub> = +15V V <sub>G2S</sub> = +10V f = 1 MHz		1.0	1.2	
Reverse Transfer	C <sub>rss</sub>	V <sub>DS</sub> = +15V, V <sub>G2S</sub> = +10V, f = 1 MHz		0.03		
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = +15V, V <sub>G1S</sub> = +4V, V <sub>G2S</sub> = +10V, I <sub>D</sub> = 18mA	8.0	10.0		mmhos
Power Gain	G <sub>ps</sub>	V <sub>DS</sub> = +15V V <sub>G1S</sub> = +4V, V <sub>G2S</sub> = +10V, I <sub>D</sub> = 18mA	13.0	16.0		dB
Noise Figure	NF	f = 500 MHz		5.0	6.0	dB
Interfering Signal Level at Gate for 1% Cross Modulation Distortion. Peak Voltage	E <sub>int</sub>	V <sub>DS</sub> = V <sub>G2S</sub> = +15V I <sub>D</sub> = 18mA Wanted Signal f = 500 MHz Interfering Signal f = 501 MHz		200		mV
Range of Automatic Gain Control	AGC (V <sub>G2S</sub> )	V <sub>DS</sub> = +15V, V <sub>G1S</sub> = +4V f = 500 MHz		40		dB
Drain to Source on Resistance	r <sub>DS</sub> (on)	V <sub>G1S</sub> = +5V, V <sub>G2S</sub> = +10V, I <sub>D</sub> = 0.1mA		90	130	ohms

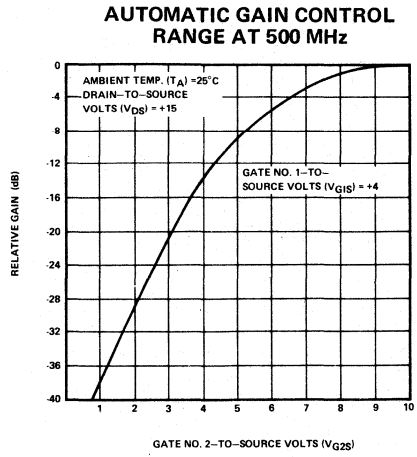
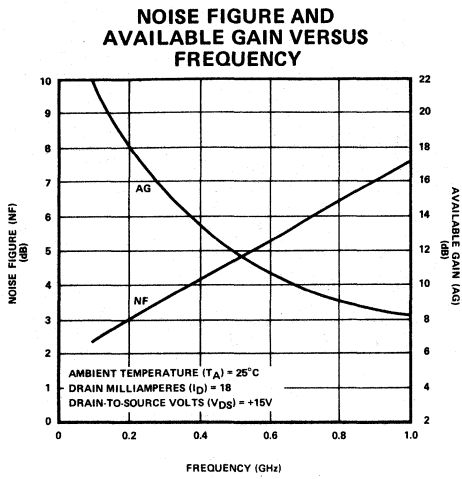
CHARACTERISTIC CURVES

PERFORMANCE CURVES



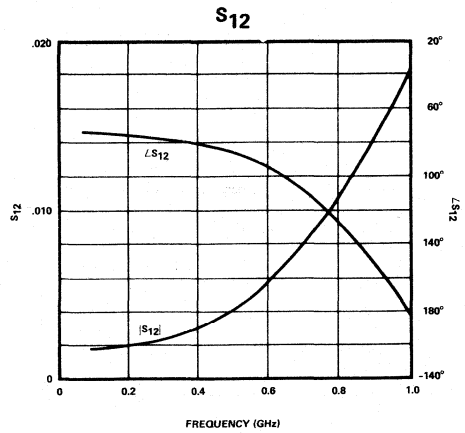
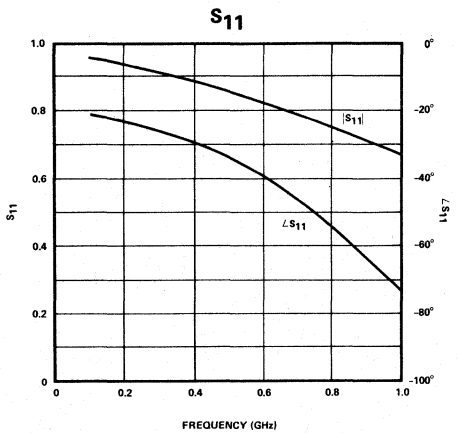
CHARACTERISTIC CURVES (Cont'd)

PERFORMANCE CURVES (cont'd)



S PARAMETERS

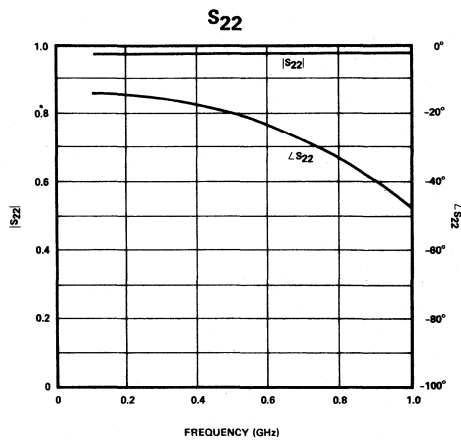
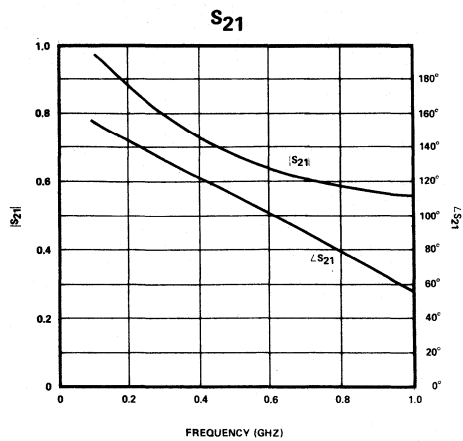
AMBIENT TEMP. ( $T_A$ ) = 25°C  
DRAIN MILLIAMPERES ( $I_D$ ) = 18  
DRAIN-TO-SOURCE VOLTS ( $V_{DS}$ ) = +15





CHARACTERISTIC CURVES (Cont'd)

S PARAMETERS (Cont'd)









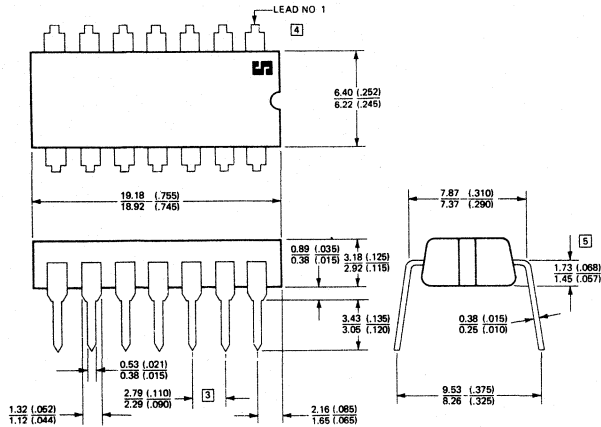
**signetics**

PACKAGE INFO  
RELIABILITY INFO  
INDUSTRY  
CROSS-REFERENCE

9



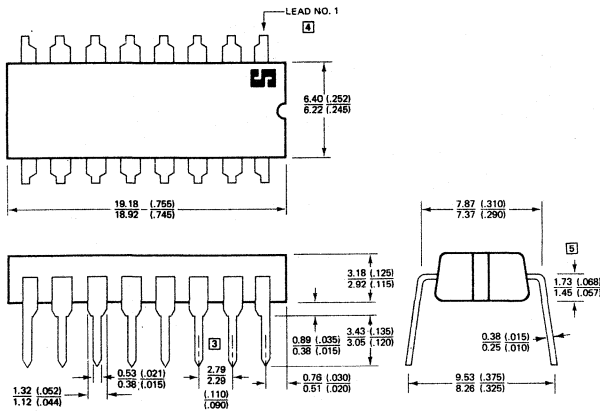
A PACKAGE



NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\Theta_{Ja} = .16^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .08^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

B PACKAGE

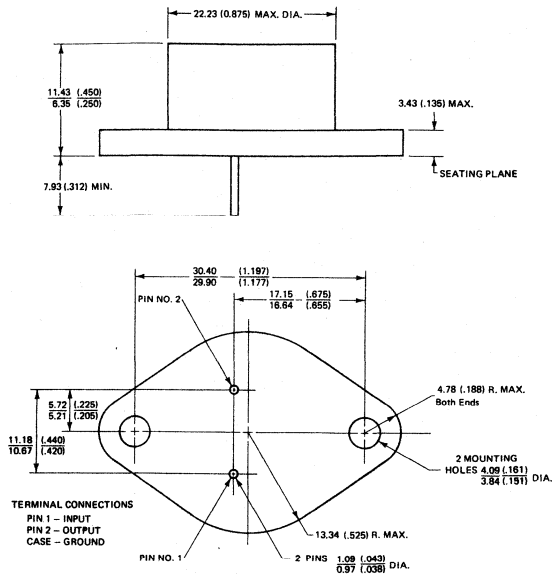


NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic.
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\Theta_{Ja} = .16^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .08^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

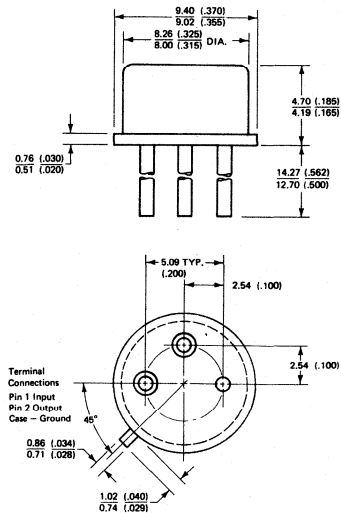
## DA PACKAGE



### NOTES:

1. Lead Material: No. 52 alloy gold plated.
2. Body Material: 1010 steel gold plated.
3. Lid Material: Steel nickel plated, weld seal.
4. All dimensions shown in parentheses are English. (Inches)

## DB PACKAGE

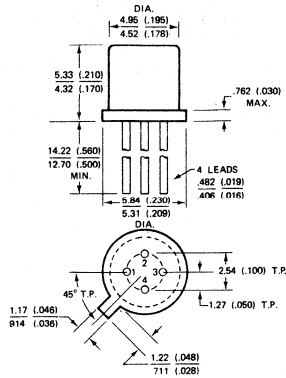


### NOTES:

1. Lead Material: Kovar or equivalent - gold plated.
2. Body Material: Eyelet, Kovar or equivalent - gold plated, glass body.
3. Lid Material: Nickel, weld seal.
4. All dimensions shown in parentheses are English. (Inches)



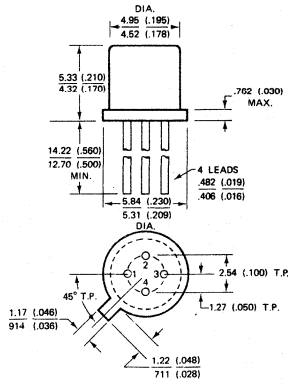
DC PACKAGE



NOTES:

1. Lead Material: Kovar or equivalent — gold plated.
2. Body Material: Eyelet, Kovar or equivalent — gold plated, glass body.
3. Lid Material: Nickel, weld seal.
4. All dimensions shown in parentheses are English. (Inches)

DE PACKAGE

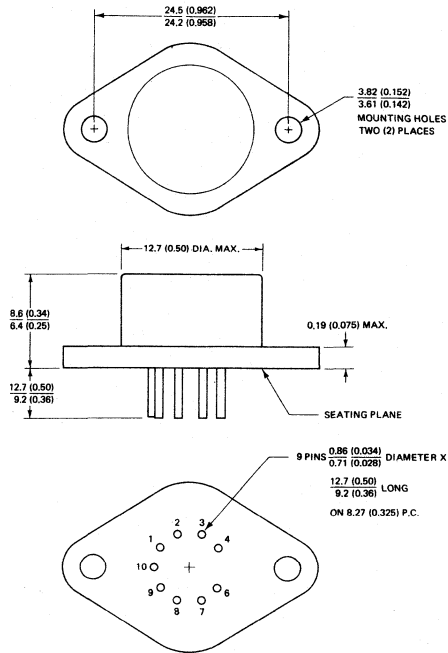


NOTES:

1. Lead Material: Kovar or equivalent — gold plated.
2. Body Material: Eyelet, Kovar or equivalent — gold plated, glass body.
3. Lid Material: Nickel, weld seal.
4. All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

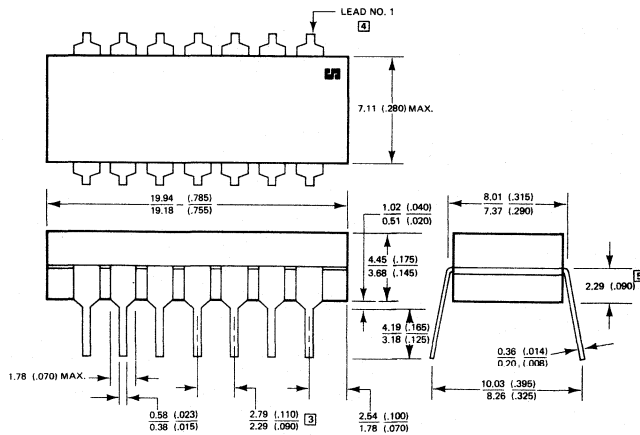
## DF PACKAGE



### NOTES:

1. Lead Material: Alloy 52, gold plated.
2. All dimensions shown in parentheses are English. (Inches)

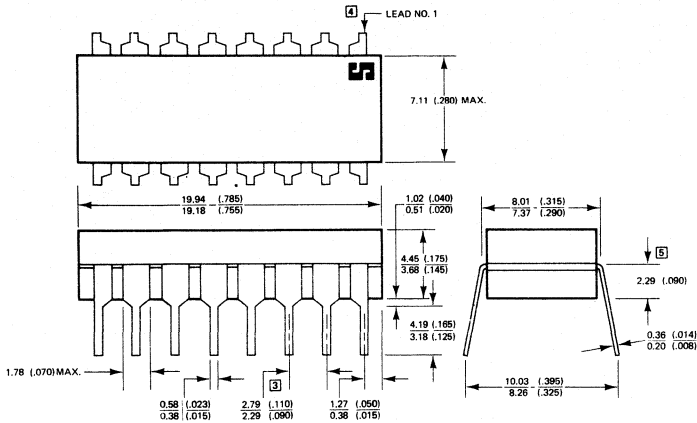
## FH PACKAGE



### NOTES:

1. Lead material: Alloy 42 or equivalent, tin plated.
2. Body material: Ceramic with glass seal.
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Thermal resistance:  $\Theta_{Ja} = .095^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .027^{\circ}\text{C}/\text{mW}$ .
7. All dimensions shown in parentheses are English. (Inches)

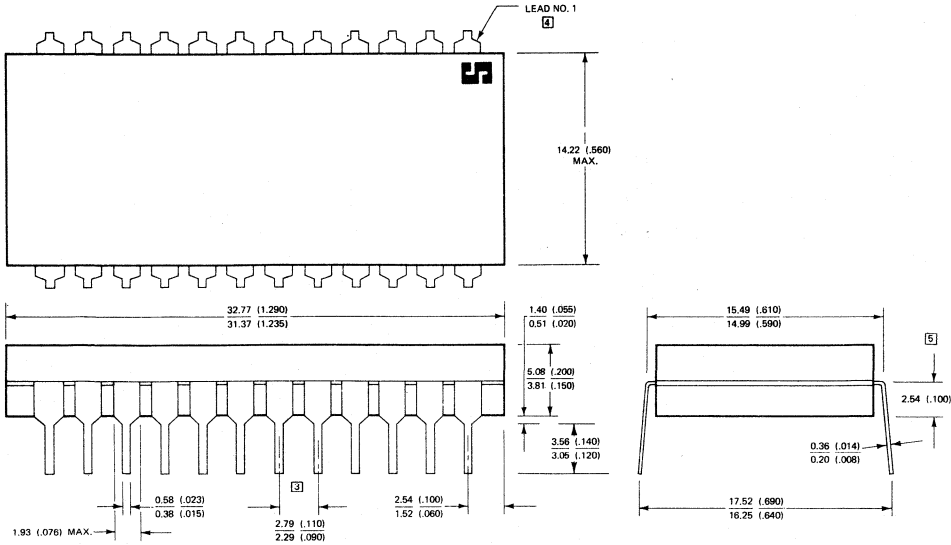
FJ PACKAGE



NOTES:

- 1. Lead material: Alloy 42 or equivalent, tin plated.
- 2. Body material: Ceramic with glass seal.
- 3. Tolerances non cumulative.
- 4. Signetics symbol denotes Lead No. 1.
- 5. Lead spacing shall be measured within this zone.
- 6. Thermal resistance:  $\Theta_{Ja} = .090^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .025^{\circ}\text{C}/\text{mW}$ .
- 7. All dimensions shown in parentheses are English. (Inches)

FN PACKAGE

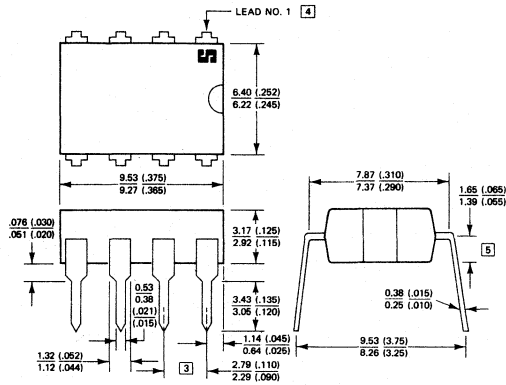


NOTES:

- 1. Lead material: Alloy 42 or equivalent, tin plated.
- 2. Body material: Ceramic with glass seal.
- 3. Tolerances non cumulative.
- 4. Signetics symbol denotes Lead No. 1.
- 5. Lead spacing shall be measured within this zone.
- 6. Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .012^{\circ}\text{C}/\text{mW}$ .
- 7. All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

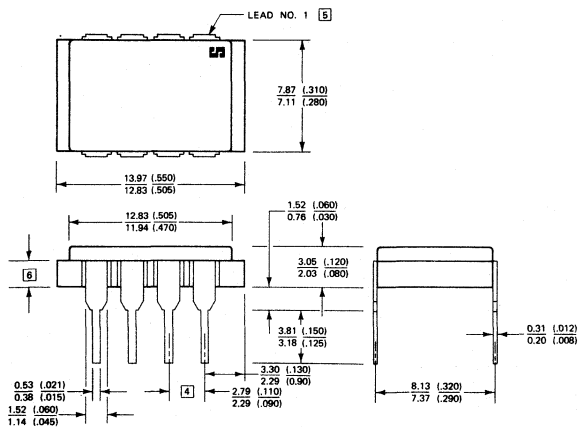
## IE PACKAGE



### NOTES:

1. Lead Material: Kovar or equivalent, gold plated.
2. Body Material: Ceramic with Kovar or equivalent.
3. Lid Material: Kovar or equivalent, gold plated, alloy seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal Resistance:  $\Theta_{Ja} = .100^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .030^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

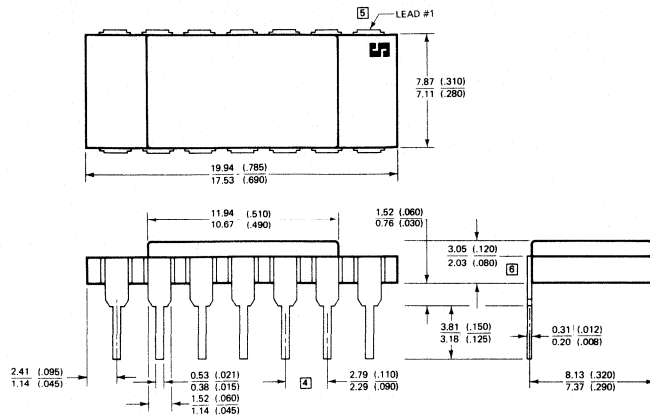
## IEA PACKAGE



### NOTES:

1. Lead Material: Kovar or equivalent, tin plated.
2. Body Material: Ceramic with Kovar or equivalent.
3. Lid Material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal Resistance:  $\Theta_{Ja} = .100^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .030^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

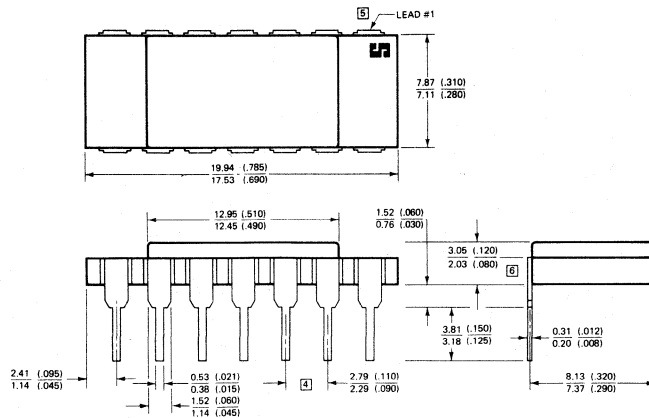
## IH PACKAGE



## NOTES:

- Lead material: Kovar or equivalent, tin plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Kovar or equivalent, gold plated, alloy seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .085^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .022^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English. (Inches)

## IHA PACKAGE

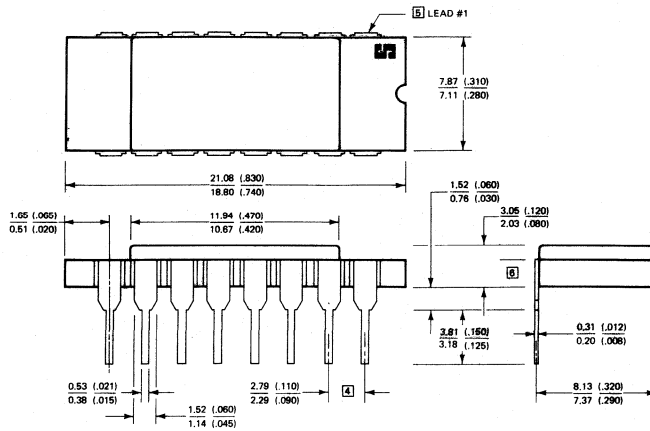


## NOTES:

- Lead material: Kovar or equivalent, tin plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Ceramic, glass seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .085^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .022^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

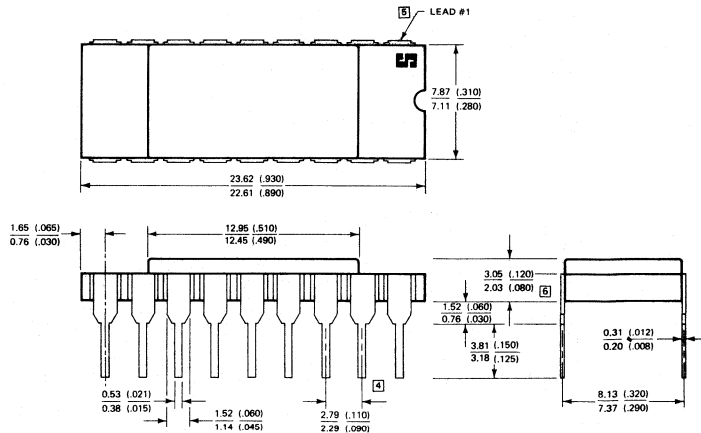
## IJ PACKAGE



### NOTES:

- Lead material: Kovar or equivalent, gold plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Kovar or equivalent, gold plated, alloy seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .080^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .020^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English. (Inches)

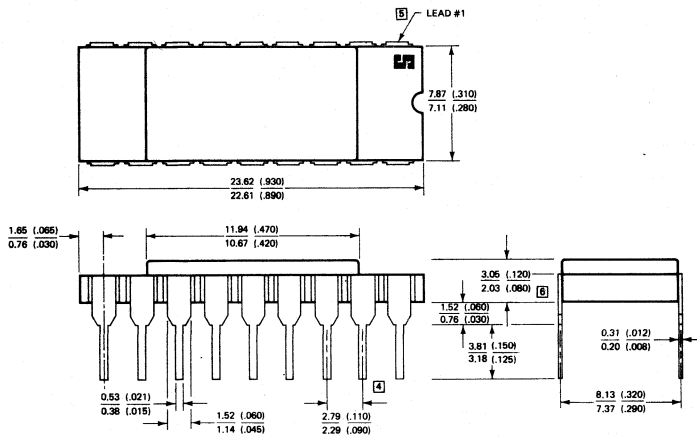
## IJA PACKAGE



### NOTES:

- Lead material: Kovar or equivalent, tin plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Ceramic, glass seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .080^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .020^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English. (Inches)

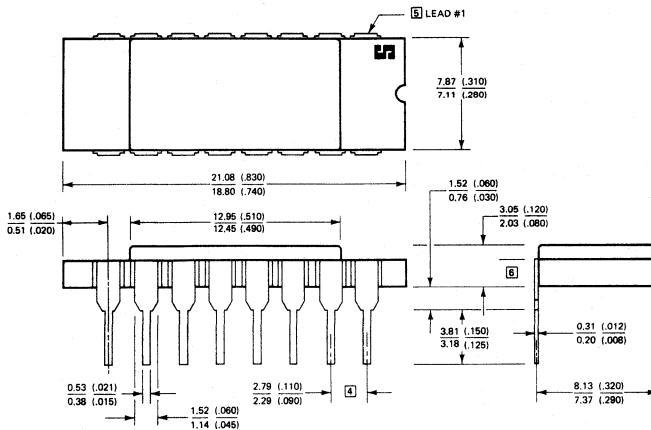
IK PACKAGE



NOTES:

1. Lead material: Kovar or equivalent, gold plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Kovar or equivalent, gold plated, alloy seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal resistance:  $\Theta_{Ja} = .075^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .018^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

IKA PACKAGE

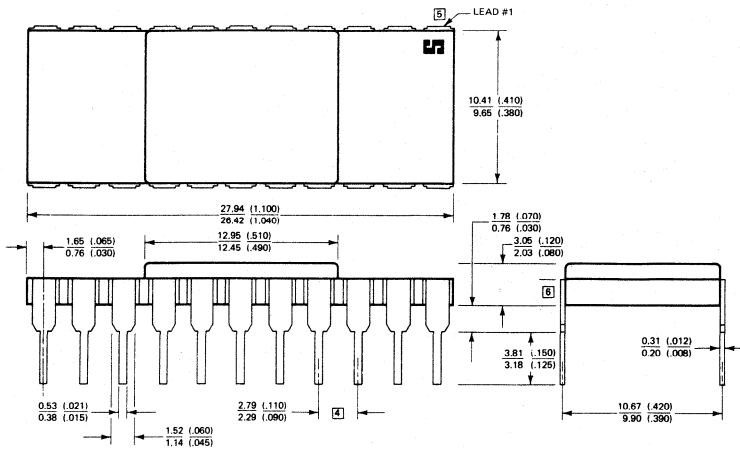


NOTES:

1. Lead material: Kovar or equivalent, tin plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal resistance:  $\Theta_{Ja} = .075^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .018^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

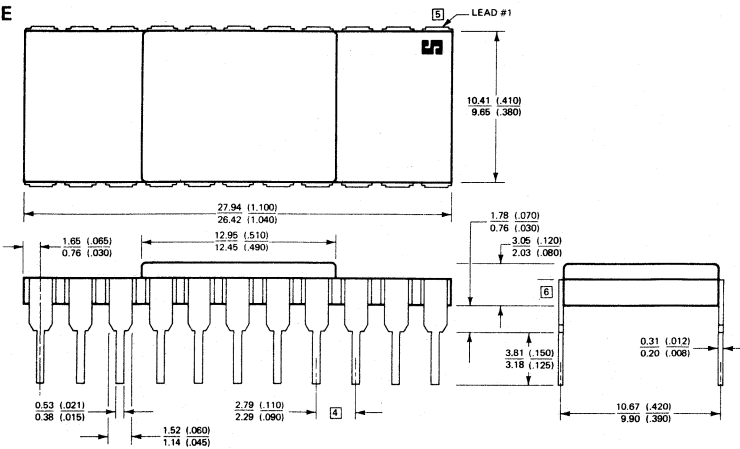
## IM PACKAGE



### NOTES:

- Lead material: Kovar or equivalent, gold plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Kovar or equivalent, gold plated, alloy seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .055^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .012^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English, (Inches)

## IMA PACKAGE

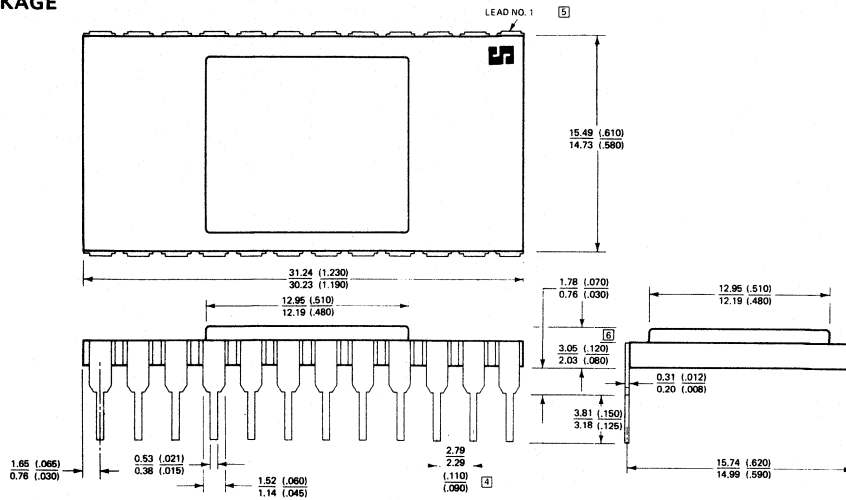


### NOTES:

- Lead material: Kovar or equivalent, tin plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Ceramic, glass seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .055^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .012^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English, (Inches)



INB PACKAGE



NOTES:

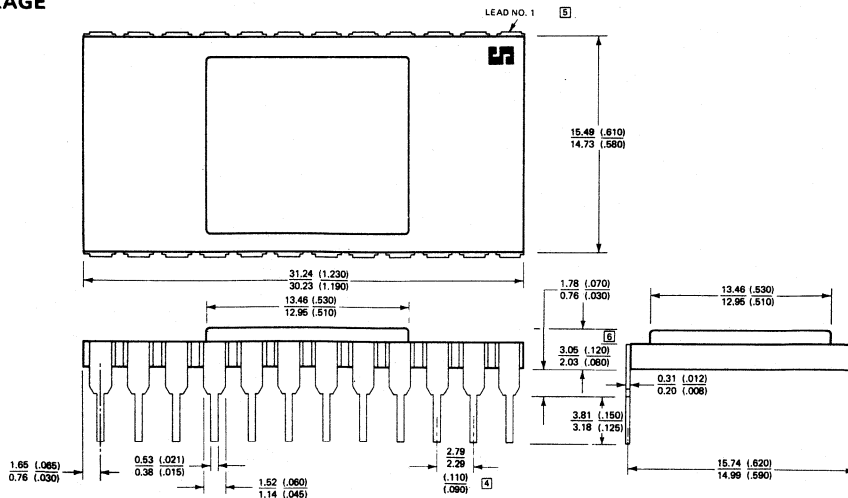
1. Lead material: Kovar or equivalent, gold plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Kovar or equivalent, gold plated, alloy seal.

4. Tolerances non cumulative.

5. Signetics symbol denotes Lead No. 1.

6. Lead spacing shall be measured within this zone.
7. Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .015^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

INC PACKAGE



NOTES:

1. Lead material: Kovar or equivalent, tin plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Kovar or equivalent, gold plated, alloy seal.

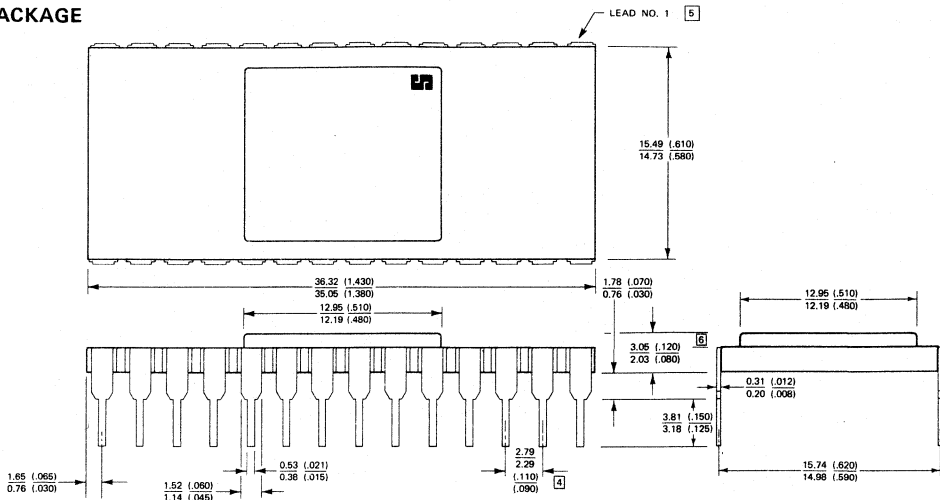
4. Tolerances non cumulative.

5. Signetics symbol denotes Lead No. 1.

6. Lead spacing shall be measured within this zone.
7. Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .015^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

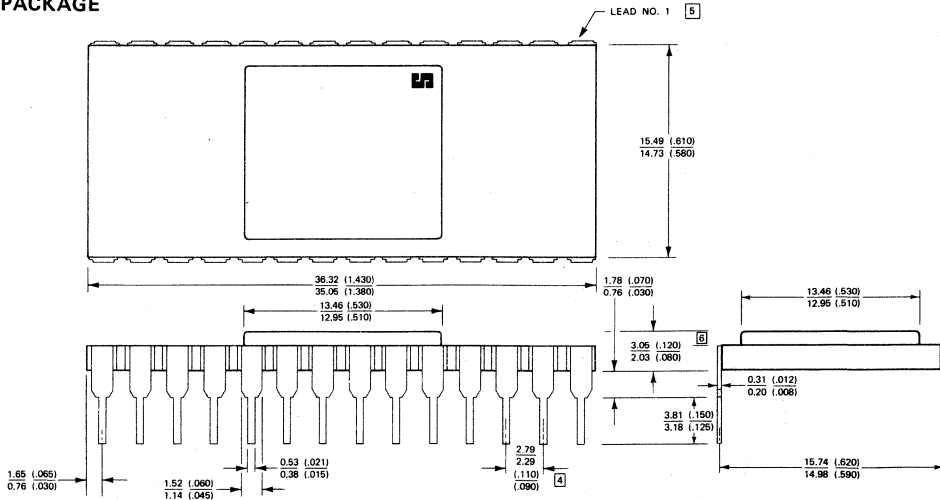
## IQ PACKAGE



### NOTES:

1. Lead material: Kovar or equivalent, tin plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .010^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

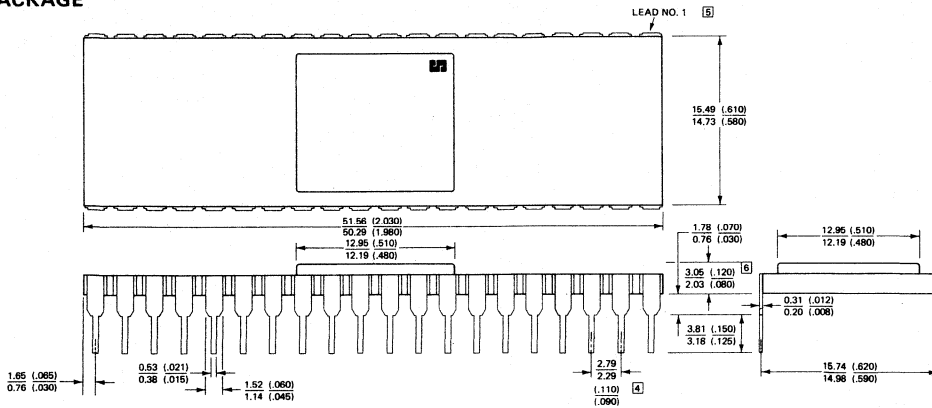
## IQA PACKAGE



### NOTES:

1. Lead material: Kovar or equivalent, tin plated.
2. Body material: Ceramic with Kovar or equivalent.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Signetics symbol denotes Lead No. 1.
6. Lead spacing shall be measured within this zone.
7. Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .010^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

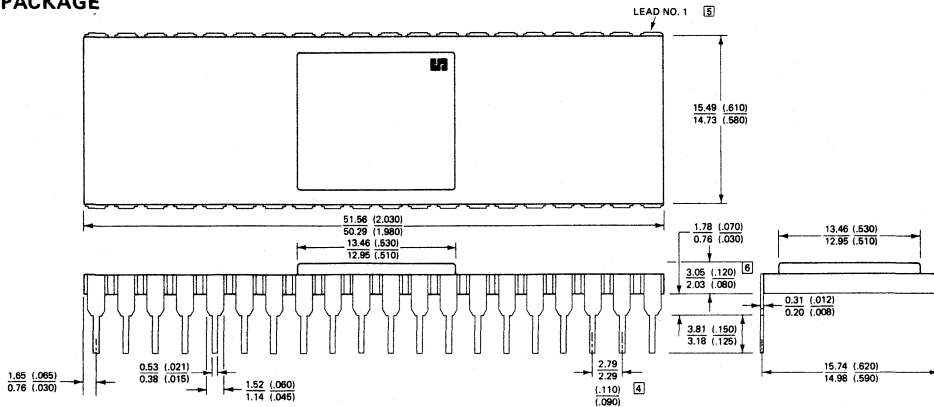
## IW PACKAGE



## NOTES:

- Lead material: Kovar or equivalent, gold plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Kovar or equivalent, gold plated, alloy seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .010^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English. (Inches)

## IWA PACKAGE

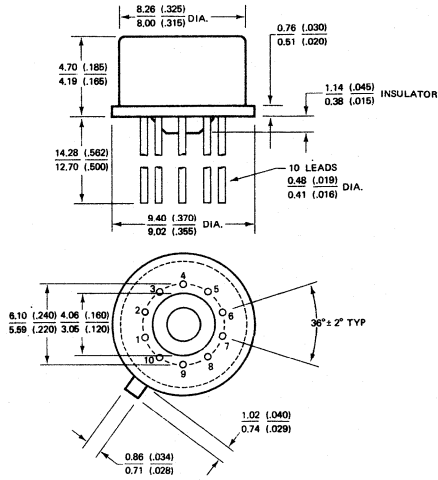


## NOTES:

- Lead material: Kovar or equivalent, tin plated.
- Body material: Ceramic with Kovar or equivalent.
- Lid material: Ceramic, glass seal.
- Tolerances non cumulative.
- Signetics symbol denotes Lead No. 1.
- Lead spacing shall be measured within this zone.
- Thermal resistance:  $\Theta_{Ja} = .050^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .010^{\circ}\text{C}/\text{mW}$ .
- All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

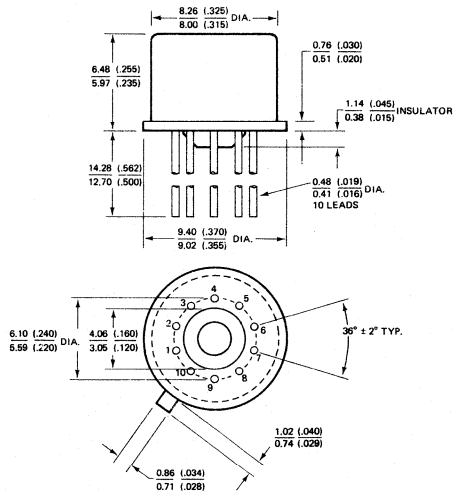
## K PACKAGE



### NOTES:

1. Lead Material: Kovar or equivalent – gold plated.
2. Body Material: Eyelet, Kovar or equivalent – gold plated, glass body
3. Lid Material: Nickel, weld seal.
4. Thermal Resistance:  $\Theta_{Ja} = .150^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .025^{\circ}\text{C}/\text{mW}$ .
5. All dimensions shown in parentheses are English. (Inches)

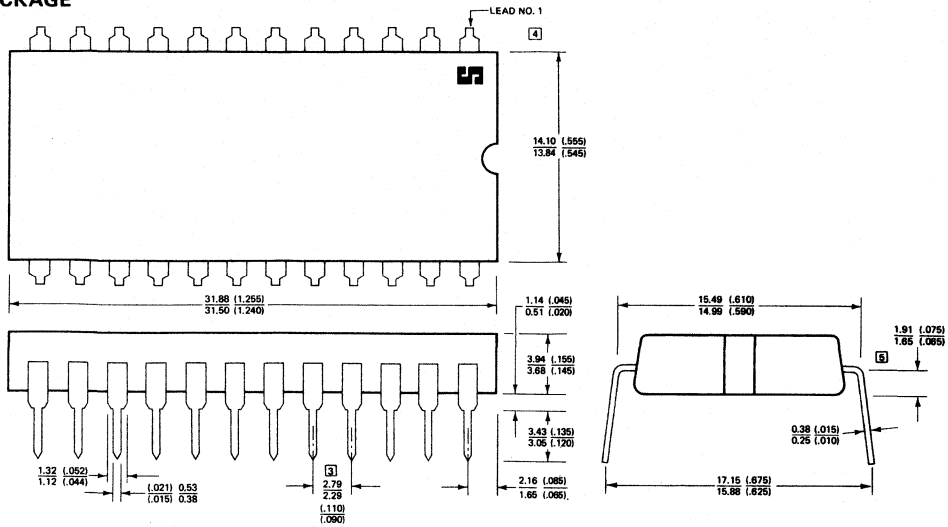
## L PACKAGE



### NOTES:

1. Lead Material: Kovar or equivalent – gold plated.
2. Body Material: Eyelet, Kovar or equivalent – gold plated, glass body.
3. Lid Material: Nickel, weld seal.
4. Thermal Resistance:  $\Theta_{Ja} = .150^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .025^{\circ}\text{C}/\text{mW}$ .
5. All dimensions shown in parentheses are English. (Inches)

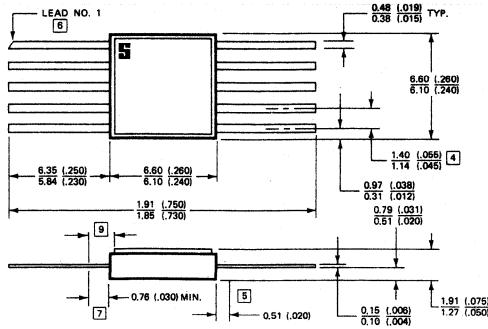
**N PACKAGE**



**NOTES:**

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\Theta_{Ja} = .12^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .05^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

**QF PACKAGE**

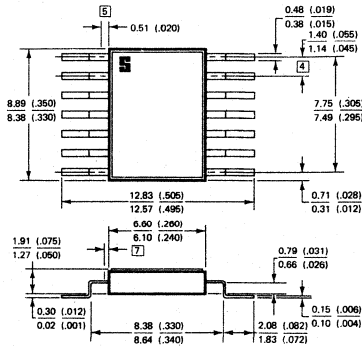


**NOTES:**

1. Lead Material: Kovar or equivalent, gold plated.
2. Body Material: Ceramic with glass seal at leads.
3. Lid Material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Thermal Resistance:  $\Theta_{Ja} = .175^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .060^{\circ}\text{C}/\text{mW}$ .
9. Maximum glass climb, lid skew, or frit squeeze out is .010.
10. All dimensions shown in parentheses are English. (Inches)

# SIGNETICS PACKAGES

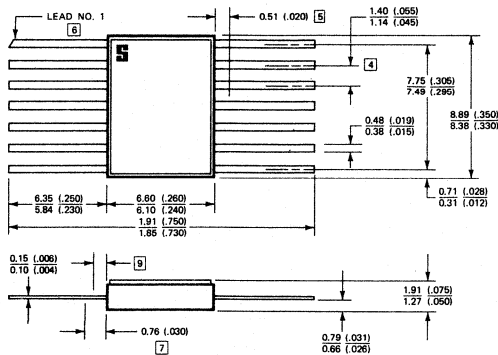
## QH PACKAGE



### NOTES:

1. Lead Material: Kovar or equivalent, gold plated.
2. Body Material: Ceramic with glass seal at leads.
3. Lid Material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Thermal Resistance:  $\Theta_{Ja} = .170^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .050^{\circ}\text{C}/\text{mW}$ .
9. Maximum glass climb, lid skew, or frit squeeze out is .010.
10. All dimensions shown in parentheses are English. (Inches)

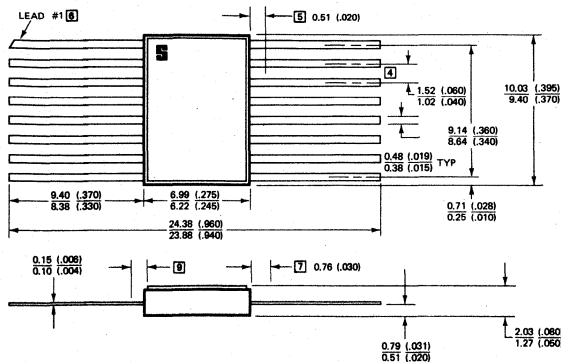
## QH PACKAGE



### NOTES:

1. Lead Material: Kovar or equivalent, gold plated.
2. Body Material: Ceramic with glass seal at leads.
3. Lid Material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol denotes Lead No. 1.
7. Maximum glass climb, lid skew or frit squeeze out .010.
8. Thermal Resistance;  $\Theta_{Ja} = .170^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .050^{\circ}\text{C}/\text{mW}$ .
9. All dimensions shown in parentheses are English. (Inches)

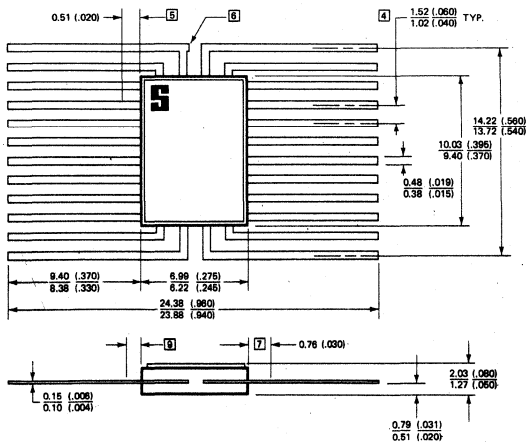
**QJ PACKAGE**



**NOTES:**

1. Lead material: Kovar or equivalent, gold plated.
2. Body material: Ceramic with glass seal at leads.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Thermal resistance:  $\Theta_{Ja} = .160^{\circ}\text{C/mW}$ ,  $\Theta_{Jc} = .045^{\circ}\text{C/mW}$ .
9. Maximum glass climb, lid skew, or frit squeeze out is .010.
10. All dimensions shown in parentheses are English. (Inches)

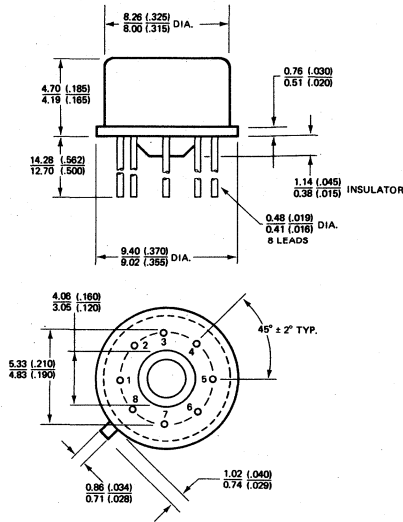
**QN PACKAGE**



**NOTES:**

1. Lead material: Kovar or equivalent, gold plated.
2. Body material: Ceramic with glass seal at leads.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Thermal resistance:  $\Theta_{Ja} = .150^{\circ}\text{C/mW}$ ,  $\Theta_{Jc} = .040^{\circ}\text{C/mW}$ .
9. Maximum glass climb, lid skew, or frit squeeze out is .010.
10. All dimensions shown in parentheses are English. (Inches)

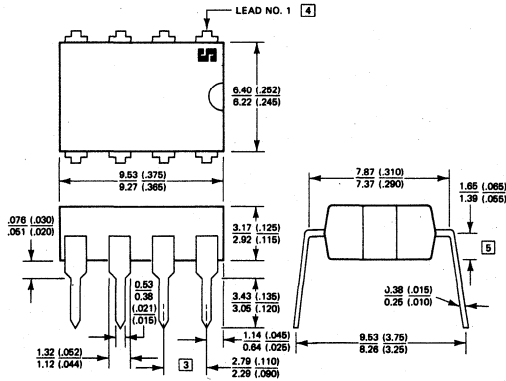
T PACKAGE



NOTES

1. Lead Material: Kovar or equivalent – gold plated.
2. Body Material: Eyelet, Kovar or equivalent – gold plated, glass body.
3. Lid Material: Nickel, weld seal.
4. Thermal Resistance:  $\Theta_{Ja} = .150^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .025^{\circ}\text{C}/\text{mW}$ .
5. All dimensions shown in parentheses are English. (Inches)

V PACKAGE

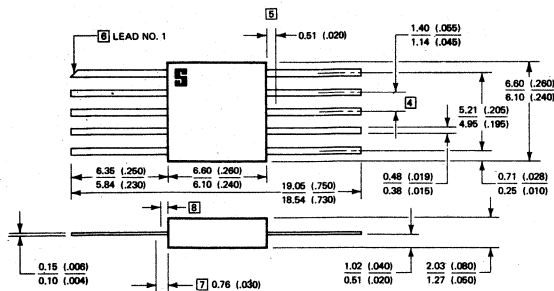


NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\Theta_{Ja} = .16^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .08^{\circ}\text{C}/\text{mW}$
8. All dimensions shown in parentheses are English. (Inches)



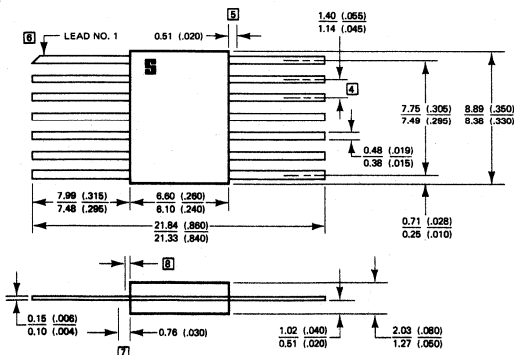
## WF PACKAGE



## NOTES:

1. Lead material: Alloy 42 or equivalent, tin plated.
2. Body material: Ceramic with glass seal at leads.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Maximum glass climb .010.
9. Thermal resistance:  $\Theta_{Ja} = .220^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .085^{\circ}\text{C}/\text{mW}$ .
10. All dimensions shown in parentheses are English.  
(Inches)

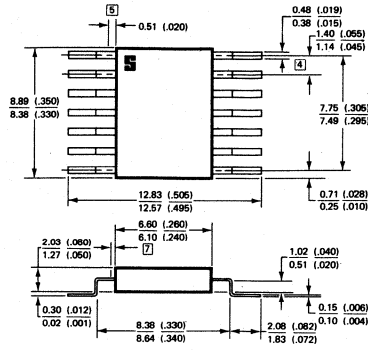
## WH PACKAGE



## NOTES:

1. Lead material: Alloy 42 or equivalent, tin plated.
2. Body material: Ceramic with glass seal at leads.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Maximum glass climb .010.
9. Thermal resistance:  $\Theta_{Ja} = .200^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .085^{\circ}\text{C}/\text{mW}$ .
10. All dimensions shown in parentheses are English.  
(Inches)

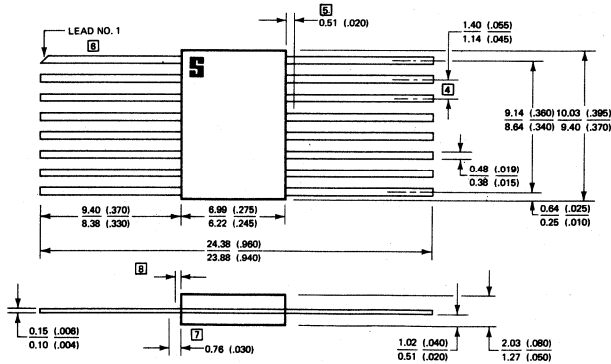
WH PACKAGE



NOTES:

1. Lead Material: Alloy 42 or equivalent, tin plated.
2. Body Material: Ceramic with glass seal at leads.
3. Lid Material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Maximum glass climb .010.
8. Thermal Resistance:  $\Theta_{Ja} = .200^{\circ}\text{C}/\text{mW}$ ;  $\Theta_{Jc} = .085^{\circ}\text{C}/\text{mW}$ .
9. All dimensions shown in parentheses are English. (Inches)

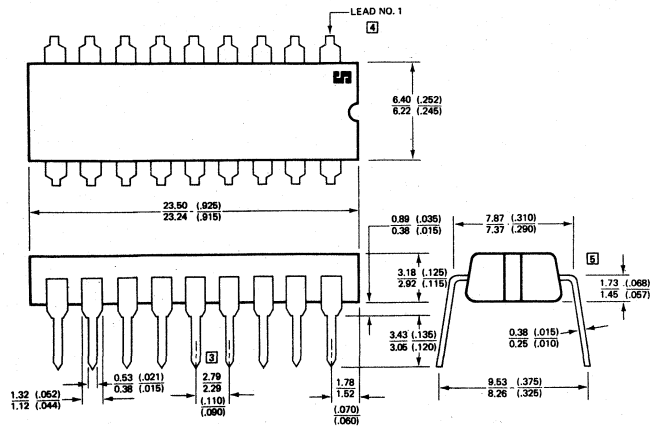
WJ PACKAGE



NOTES:

1. Lead material: Alloy 42 or equivalent, tin plated.
2. Body material: Ceramic with glass seal at leads.
3. Lid material: Ceramic, glass seal.
4. Tolerances non cumulative.
5. Lead spacing shall be measured within this zone.
6. Signetics symbol or angle cut denotes Lead No. 1.
7. Recommended minimum offset before lead bend.
8. Maximum glass climb .010.
9. Thermal resistance:  $\Theta_{Ja} = .195^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .085^{\circ}\text{C}/\text{mW}$ .
10. All dimensions shown in parentheses are English. (Inches)

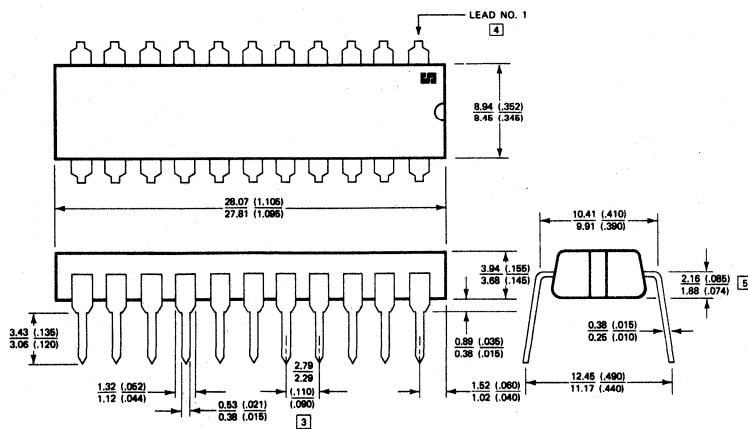
## XA PACKAGE



## NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\Theta_{Ja} = .16^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .08^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

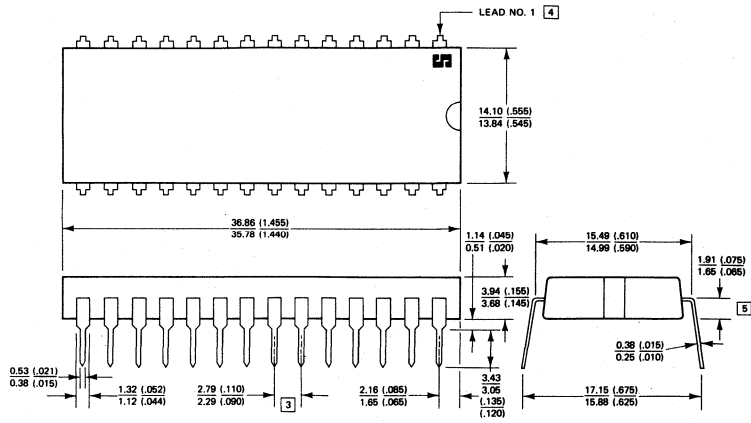
## XC PACKAGE



## NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic.
3. Tolerances non cumulative.
4. Signetics symbol denotes Lead No. 1.
5. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\Theta_{Ja} = .125^{\circ}\text{C}/\text{mW}$ ,  $\Theta_{Jc} = .055^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English. (Inches)

XF PACKAGE



NOTES:

1. Lead Material: Alloy 42 or equivalent.
2. Body Material: Plastic
- [3]. Tolerances non cumulative.
- [4]. Signetics symbol denotes Lead No. 1.
- [5]. Lead spacing shall be measured within this zone.
6. Body dimensions do not include molding flash.
7. Thermal Resistance:  $\theta_{Ja} = .12^{\circ}\text{C}/\text{mW}$ ,  $\theta_{Jc} = .05^{\circ}\text{C}/\text{mW}$ .
8. All dimensions shown in parentheses are English, (Inches)

## INTRODUCTION

Increasingly, users are demanding ultra high quality and reliability commercial temperature range ICs for their use in certain electronic systems. This trend toward a "Zero Defects" philosophy has been prompted by the inability of previously available "one or two percent" defective device lots to meet board rework cost requirements and system reliability goals.

The need for nearly perfect, but low cost, devices is being met by the industry with varying degrees of success. Several IC manufacturers have programs which partially meet these requirements, and many users have implemented specifications designed to accomplish this goal.

Signetics has been supplying devices to these general requirements for some time, but only now, and for the first time in the industry, has a fully evaluated and comprehensive program been instituted. We call it SUPR DIP.

## DESCRIPTION OF PROCESS STEPS (see Page 7)

SUPR DIP utilizes the best provisions of various user specifications and adds a few of our own. SUPR DIP is a COMPREHENSIVE program which results in the HIGHEST QUALITY and RELIABILITY commercial products AVAILABLE IN THE INDUSTRY. Other suppliers' user specifications offer SOME of the advantages of our program, but only SUPR DIP gives ALL of the following provisions:

- Visual Die Sort Inspection, MIL-STD-883, Method 2010, Condition B Criteria

- Preseal Visual Inspection, MIL-STD-883, Method 2010, Condition B Criteria
- 100% Thermal Shock, MIL-STD-883, Method 1011, Condition A Criteria
- 100% Production Electrical Testing
- 100% High Temperature Functional Testing for elimination of functional rejects and temperature sensitive (intermittent) bonds
- Outgoing Lot Quality Acceptance Testing including 0.15% AQL for functionality and 0.15% to 1.0% for other electrical and mechanical criteria

## BENEFITS

The above processing steps are efficiently performed in volume, and users realize the following benefits at both

### LOW INITIAL COST and LOW EVENTUAL COST:

- Eliminates need for 100% incoming electrical testing and mechanical inspection
- No need for additional preconditioning prior to board assembly
- Significantly reduces requirement for board rework (page 8)
- Reduction in system field failures
- Permits the following Signetics GUARANTEES:

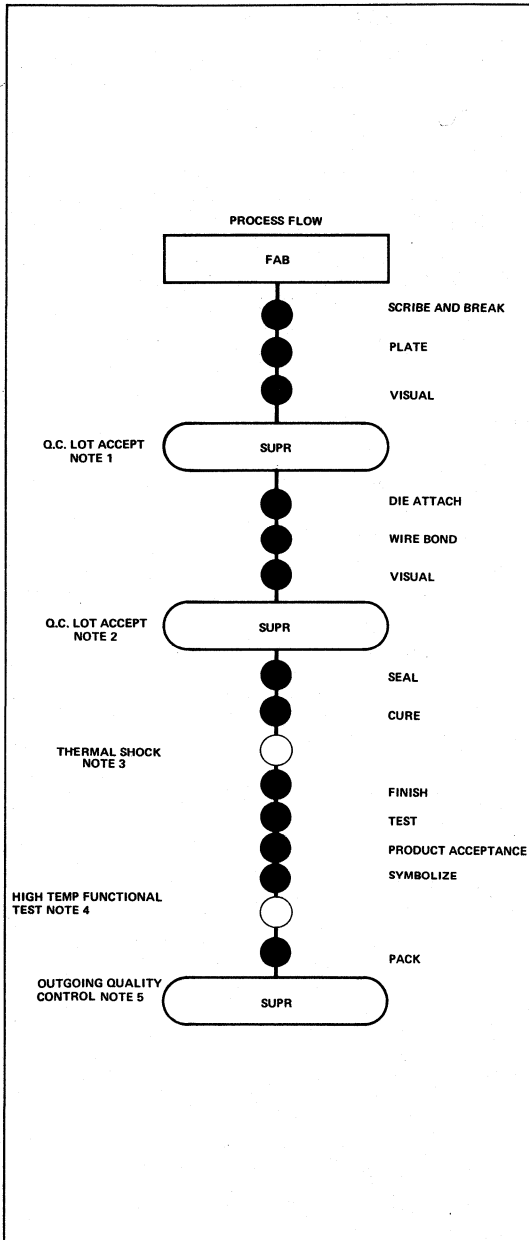
## GUARANTEES

TEST	CONDITIONS	AQL	CUMULATIVE	NOTES
Electrically Functional	25°C	0.15%	0.15%	1
	100°C	0.15%		
DC	25°C	.65%	2.5%	
	At Temperatures	1.0%		
AC	25°C	1.0%		
Mechanical	Major	.25%	1.0%	2
	Minor	1.0%		

NOTE 1: The functional test not only checks for opens and shorts but also performs an operating test where the device is driven from standard outputs and drives inputs under full load.

NOTE 2: MAJOR DEFECTS: those that make the circuit inoperable such as missing pin, wrong symbol, no solder, shorted pins, holes in package. MINOR DEFECTS: physical dimensions, illegible type, solderability to MIL-S-202C-208B.

**WHAT FLOW AND GUARANTEES DO I GET WITH SUPR?**



**PROCESS NOTES AND DESCRIPTIONS**

**NOTE 1: Q.C. Lot Acceptance of Die**  
 From reports covering all reported 1971 failures an analysis was compiled to determine the need for improved inspection at die sort. The inspection derived from this study was to lot accept to a 4.0% AQL to MIL-STD-883, 2010B. This is statistically adequate to reject all lots with repetitive type

masking errors and lots that exhibit potential high yield losses. Critical random defects which constitute reliability problems and which may not be detected at final test are inspected to a 1.0% AQL. These include:

1. scratches
2. smears
3. glassivated bonding pads

**NOTE 2: Q.C. Lot Acceptance of Preseal Parts**  
 From the above study an analysis was completed on parts prior to encapsulation. The same inspection at this point is being performed in accordance with MIL-STD-883, 2010-B to a 2.5% AQL, and with critical defects to a 0.65% AQL. Critical defects include:

1. scratches caused by assembly operators
2. contamination
3. smeared ball bonds on bonding pads decreasing the aluminum

**NOTE 3: Preconditioning**  
 Various types of preconditioning were examined including thermal shock, temperature cycle, and high temperature storage. Thermal shock (MIL-STD-883, 1011, A) was selected as the most effective method of removing potential package problems that could not be detected by other processing screens. This processing weakens loose bonds so that they may be tested out at temperature without degrading the quality of good bonds. Other tests have either no effect on quality and reliability or significantly degraded the good parts during the preconditioning period.

Some users, attempting to incorporate tighter screening, have instituted various preconditioning steps before testing or board assembly. Many of these steps create problems which would not occur if preconditioning was performed prior to shipment. Examples of a few of these problems are opens at high temperature due to extremes of thermal shock or temperature cycles, symbolization coming off after exposure to liquids used for shock testing, handling loss and mechanical damage, solderability problems due to contamination within ovens.

**NOTE 4: High Functional Temperature Test**  
 Analysis of user incoming quality and system failure reports has yielded four significant results:

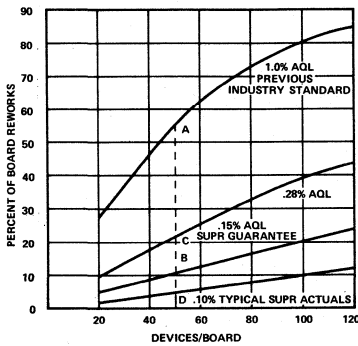
- A. Due to supplier processing and handling from final test to shipment, parts may become mixed to a low percent defective.
- B. Some devices, due to internal differential expansion coefficients, become non-functional when operated in a system in which the ambient is above room temperature and the junctions receive continuous power. This is normally due to weak bonds. These parts create considerable system detection problems since they test good at room temperature and may also become system life test failures.

C. Most customers building boards of 40 or more units complexity perform 100% parts testing upon receipt of a shipment. This is to obtain a low percentage board rework. This is normally performed at room temperature using a large test system. These testers have the potential for destroying or degrading units due to faulty relay controls which force excessive currents into devices. In an ordinary electronic system, parts are never subjected to these conditions. In many cases, this type of inspection results in a greater percent lot defective than was received and can result in additional board rework. 100% testing normally only reduces percent defective to a .28% AQL level. (see Page 8)

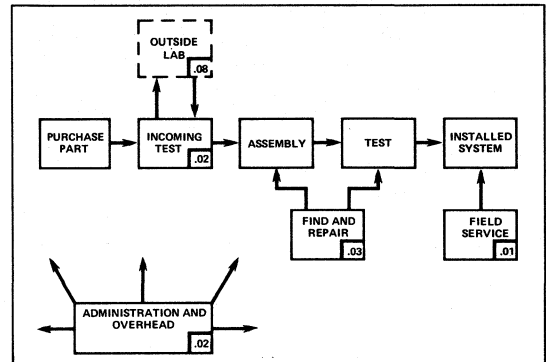
1. One sample is selected to check functionality, using a tester which has no potential for degrading units. No relay switching or current forcing modules should be used.
2. From this sample another sample is tested for AC and DC conformance to specifications. Only devices which have a marginal AC or high temp quality history need be tested.
3. In most cases skip lot testing can be instituted immediately.

In this manner a great savings can be realized in incoming control and board rework costs.

**AQL LEVELS VS. BOARD REWORKS**



**A TYPICAL IC USER'S ASSEMBLY FLOW AND SOME INDUSTRY AVERAGE COSTS**



D. Most integrated circuits will never be used in a circuit that requires all worst case load and threshold conditions. If a part will function under load at 100 degrees C ambient, it will consistently work in a system.

Signetics has addressed to all these problems by designing a test system that repetitively tests devices functionally at a temperature in excess of 100 degrees C. This testing circuit is the same electrical environment as in a computer.

Costs added to parts because of quality problems (based on current industry averages)

Incoming inspection (sampling, 100% test, preconditioning) labor and material only. Outside labs were kept separate since they tend to distort this number. Present average cost for outside lab usage is \$.08 per part. .02

Find and repair defective parts in boards and systems. This includes location of defects, scrapped parts, replacement of bad parts, engineering support during system burn-in. Labor and material only. .03

Field service support. Labor, material, travel, revenue lost due to equipment being down. Calculated only on first year expenses. No customer ill will, lost accounts, maintenance, organization overhead is included. .01

Administration and overhead. Test equipment for parts and systems (depreciation, only) support costs of this equipment, inventory of parts and systems necessary because of delays due to quality problems. No additional hidden costs such as added supervision, field service overhead, quality and reliability overhead is included. .02

TOTAL (not including outside labs) .08  
 SUPR DIP WAS ENGINEERED TO CUT THIS EXPENSE BY ONE ORDER OF MAGNITUDE

**NOTE 5: Outgoing Quality Control**

The task of this function is to ensure that parts have been processed to the required flow and that the tightened inspection criteria are being met. An additional sample will be selected to assure electrical specification conformance. Each shipment will be sealed by Quality Assurance personnel.

**RECOMMENDED INCOMING TEST**

Signetics recommends that parts from this program be sampled at incoming inspection by using the following technique:

# SIGNETICS SURE 883 PROGRAM

## FOR DIGITAL DEVICES BULLETIN 5001A

The Signetics SURE\*/883 Program consists of a combination of 100 percent and statistical sample tests designed to assure specified performance, continuing uniformity, and long term reliability of Signetics products. These tests are made regularly at no extra cost to the user and are performed in addition to the 40 quality assurance inspections and tests to which every circuit is subjected before final seal. The tests, tabulated below for the specifier's convenience, are performed in accordance with the following conditions, sequence, and schedules on equipment calibrated to meet all requirements of MIL-Q-9858A and MIL-C-45662A.

Every circuit of every lot is processed to the environmental screens shown in Table I. These screens are performed in production and include 100% final production electrical tests. Any unit failing either the environmental screens or the final production electrical tests is rejected and removed from the lot.

After completion of Table I tests, each manufacturing lot is sampled and tested by Quality Assurance for conformance to the requirements of Table II. The unsampled portion of the lot is held pending acceptance of the lot sample. Detailed electrical test limits and conditions applicable to each subgroup are shown in the Electrical Characteristics table of the individual part type data sheets.

Tables IIIA, IIIB, and IIIC provide a complete process qualification and verification program in accordance with the conditions of MIL-STD-883, Group A, B and C tests. These tests are performed once in every 90 day manufacturing period, on representative devices from each standard production die process family and on each production package family. The representative circuits and packages selected are changed routinely, and the tests performed monitor and qualify all structurally similar devices produced by the same process and production during that period. A summary of these test results is available on request at the time of order placement.

\* Systematic Uniformity and Reliability Evaluation

All of the applicable Electrical Parameters of Table IIIA are performed at pretest on the Table IIIC samples. This provides the MIL-STD-883 electrical parameter and design verification Group A tests. These tests are performed on representative circuit types from every die process family type in manufacturing during this period.

Table IIIB consists of the package oriented qualification environmental stress tests of MIL-STD-883, Groups B and C. Representative samples from each package product family type are monitored and qualified every 90 day period by these tests. A common device is used as the die type for these package and assembly qualification tests.

Table IIIC consists of the die process oriented qualification electrical stress or operational tests at high temperature per MIL-STD-883, Groups B and C. Representative devices from each die process family are monitored and qualified every 90 day period by these tests. The package type is randomly selected as applicable.

An additional screening series is available at extra cost. Details are given in Table V, MIL-STD-883, method 5004, high reliability screening.

**Table I — 100% Production Screen Tests**

TEST	CONDITIONS
Preseal Visual Thermal Shock	High Power — Low Power Liquid to Liquid, 5 Cycles, 60 Seconds at 0°C, 60 Seconds at 100°C, transfer time 5 Seconds. (See Note 1.)
Centrifuge	Y <sub>1</sub> Axis; 30,000 g minimum, 1 minute. (See Note 1.)
Hermeticity	Gross leak test (Bubble Test). (See Note 1.)
Production Electrical Tests	

**Table II — Signetics Acceptance Tests (See Notes 2 and 3)**

SIGNETICS SUBGROUP	TEST	CONDITIONS	AQL	MIL-STD-105 INSPECTION LEVEL
A-1	Visual and Mechanical Inspection	MIL-STD-883 Method 2009	1.0%	II
A-2	DC Parameters	T <sub>A</sub> = +25°C	1.0%	II
A-3	DC Parameters	T <sub>A</sub> = +25°C	1.0%	II
A-4	DC Parameters	T <sub>A</sub> = +125°C	1.0%	II
A-5	DC Parameters	T <sub>A</sub> = -55°C	1.0%	II
A-6	AC Parameters	T <sub>A</sub> = +25°C	1.0%	II



**TABLE IIIA. MIL-STD-883 GROUP A  
ELECTRICAL TESTS**

MIL-STD-883 GROUP A SUBGROUP	SIGNETICS SUBGROUP	TEST DESCRIPTION
A1	A-2, A-3	Static tests at 25°C
A2	A-4	Static tests at maximum rated operating temperature.
A3	A-5	Static tests at minimum rated operating temperature.
A4	A-6	Dynamic tests at 25°C.
A5	C-2, when applicable	Dynamic tests at maximum rated operating temperature.
A6	C-2, when applicable	Dynamic tests at minimum rated operating temperature.
A7	*	Functional tests at 25°C.
A8	A-4, A-5	Functional tests at maximum and minimum rated operating temperatures.
A9	A-6	Switching tests at 25°C.
A10	C-2, when applicable	Switching tests at maximum rated operating temperature.
A11	C-2, when applicable	Switching tests at minimum rated operating temperature.

**TABLE IIIB. MIL-STD-883 GROUPS B AND C ENVIRONMENTAL TESTS**

MIL-STD-883 GROUP B & C SUBGROUP	TEST DESCRIPTION	MIL-STD-883 METHOD	CONDITIONS	LTPD
B <sub>1</sub>	Physical Dimensions	2008	Test Condition A	15
B <sub>2</sub>	Marking Permanency Visual and Mechanical Bond Strength	2008 2008 2011	Test Condition B, Para. 3.2.1 Test Condition B Test Condition D	4 devices/no failure 1 device/no failure 15
B <sub>3</sub>	Solderability	2003	Solder Temperature 260°C ±10°C	15
B <sub>4</sub>	Lead Fatigue Hermeticity a. Fine b. Gross	2004 1014	Test Condition B2 See Note 4 Test Condition A or B Test Condition C	15
C <sub>1</sub>	Pre-Test Electrical Parameters Thermal Shock  Temperature Cycle  Hermeticity a. Fine b. Gross Moisture Resistance End Point Electrical Parameters FAILURE CRITERIA	1011  1010  1014  1004	Signetics Subgroup A-3  15 Cycles. Test Condition C, +150°C to -65°C 10 Cycles. Test Condition C, 150°C to -65°C See Note 4 Test Condition A or B Test Condition C Omit initial conditioning.  Signetics Subgroup A-3 Refer to Table IV.	15
C <sub>2</sub>	Pre-Test Electrical Parameters Mechanical Shock Vibration Variable Frequency Constant Acceleration End Point Electrical Parameters FAILURE CRITERIA	2002  2007 2001	Signetics Subgroup A-3 Test Condition B  Test Condition A Test Condition E  Signetics Subgroup A-3 Refer to Table IV.	15
C <sub>3</sub>	Salt Atmosphere	1009	Test Condition A. Omit initial conditioning.	15
C <sub>4</sub>	Pre-Test Electrical Parameters High Temperature Storage End Point Electrical Parameters FAILURE CRITERIA	1008	Signetics Subgroup A-3  T <sub>A</sub> = +150°C, t = 1000 hours  Signetics Subgroup A-3 Refer to Table IV.	λ = 15

**TABLE IIIC. MIL-STD-883 GROUPS B AND C HIGH TEMPERATURE  
OPERATING LIFE TESTS**

MIL-STD-883 GROUP B & C SUBGROUP	TEST DESCRIPTION	MIL-STD-883 METHOD	CONDITIONS	LTPD
	Pre-Test and Design Verification Electrical Parameters		Table IIIA as applicable, data sheet groups A & C.	
C <sub>5</sub>	High Temperature Operating Life  End Point Electrical Parameters FAILURE CRITERIA	1005	Test Condition D or E as applicable. T <sub>A</sub> = +125°C or +85°C, per Part Data Sheet. t = 1000 hours.  Signetics Subgroup A-3 Refer to Table IV.	λ = 10

\*Signetics performs a truth table test.

**Table IV — Signetics Failure Criteria**

TEST	"1" Input Current	"1" Output Voltage	"0" Input Current	"0" Output Voltage	Expansion Node Current
LIMITS	Data Sheet Limits and: 10X Initial Value for DTL 5X Initial Value for TTL	Data Sheet Limits and: ±20% Initial Value	Data Sheet Limits ±20% Initial Value	Data Sheet Limits and: ±0.1V	Data Sheet Limits and: ±20% Initial Value

**Optional High Reliability Screening**

To maximize reliability in critical application, the Optional High Reliability Screening of Table V provides for three levels of 100% screening per MIL-STD-883, Method 5004 at extra cost. This series eliminates the necessity for special specification, minimizes cost and provides the shortest possible delivery time. This series is applied after the normal Group A acceptance test. Circuits subjected to this Preconditioning Series are clearly distinguishable from standard products in the following ways:

- Individual serial number on each circuit (Class A only).
- The first letters of a part number are either RA, RB, or RC.  
 RA = Class A  
 RB = Class B  
 RC = Class C  
 i.e., RA8880J = 100% screening of Table V, Class A.
- Individual device variables parametric test data is supplied with each shipment (Class A only).

Consult your local representative for price information. Device types should be specified with the appropriate letter prefixes.

**Notes:**

- Not applicable to solid molded packaged devices.
- All test equipment calibrated to meet requirements of MIL-Q-9858A and MIL-C-45662A.
- Detailed tests, conditions, and limits applicable to each subgroup are given in the Signetics data sheet ELECTRICAL CHARACTERISTICS table. See Table IIIA for the corresponding Group A tests of MIL-STD-883.
- The Hermeticity tests are not employed for solid molded packages.
- Class B and Class C may be subjected to thermal shock as an alternate.
- The test sequence of fine and gross leak may be reversed when fluorocarbons are utilized for gross leak.
- The individual MIL-STD-883 Test Methods are, in many cases designed to "stand alone" as a sole screen or sole Group B environmental sampling test. But since 5004 specifies a screening series or flow, some of the measurements, etc., specified in an individual Test Method are not intended to be applicable in the screening series.

**TABLE V — MIL-STD-883 METHOD 5004, HIGH RELIABILITY SCREENING**

TEST	MIL-STD-883 METHOD	CLASS A	CLASS B	CLASS C	CLARIFICATIONS (See Note 7)
Internal Visual (pretest)	2010.1	Cond. A	Cond. B	Cond. B	Test Condition A, Paragraph 3.1.1.7, a, delete the words "and parameter"
Stabilization Bake	1008 (24 hours)	Cond. C	Cond. C	Cond. C	Condition C (150°C) max. for au/al metallization system. Cond. D (200°C) max. for al/al metallization system. No electrical measurements at this point.
Thermal Shock	1011	Cond. C	Not required. NOTE 5	Not required. NOTE 5	Cond. C (150°C) max. for au/al metallization system. Cond. D (200°C) max. for al/al metallization system. No electrical measurements, no external visual inspection at this point.
Temperature Cycling	1010	Cond. C	Cond. C NOTE 5	Cond. C NOTE 5	(150°C) max. for au/al metallization system. Cond. D (200°C) max. for al/al metallization system. No electrical measurements, no external visual inspection, no hermeticity tests at this point.
Mechanical Shock	2002, Y1 plane only	Cond. B	Not Required	Not Required	No electrical measurements at this point.
Centrifuge	2001	Cond. E Y2 then Y1 plane	Cond. E Y1 plane	Cond. E Y1 plane	
Hermeticity A. Fine Leak B. Gross Leak	1014, Note 6 (Hermetic devices only)	Cond. A or B Cond. C	Cond. A or B Cond. C	Cond. A or B Cond. C	
Critical Electrical Parameters	Signetics Subgroup A.3	Read and Record	Not Required	Not Required	
Burn-In Test	1015, T <sub>A</sub> = +125°C	240 hours Cond. D or E (as applicable)	168 hours Cond. D or E (as applicable)	Not Required	
Critical Electrical Parameters	Signetics Subgroup A.3	Read and Record	Not Required	Not Required	
Signetics FAILURE CRITERIA		Table IV	Not Required	Not Required	
Reverse Bias Burn In	1015, T <sub>A</sub> = +150°C t = 72 hours	Cond. A or C	Not Required	Not Required	Required only when specified in the applicable procurement document. Signetics standard burn-in (above) includes reverse bias of unused junctions.
Final Electrical Test	Perform go no go measurements of Signetics Subgroup A Parameters	Signetics Subgroups A.2, A.4, A.5, A.6. Functional tests, truth table when applicable	Signetics Subgroups A.2, A.3. Functional tests, truth table when applicable	Signetics Subgroups A.2, A.3 Functional tests, truth table when applicable	
Radiographic Inspection	2012	Yes	Not Required	Not Required	
External Visual	2009	Yes	Yes	Yes	

**SIGNETICS QUALIFICATION AND SCREENING PROGRAM IN ACCORDANCE WITH MIL-STD-883, METHOD 5004 & 5005**

The Signetics SURE\*/883 Program consists of a combination of 100 percent and statistical sample tests designed to assure specified performance, continuing uniformity, and long term reliability of Signetics products. These tests are made regularly at no extra cost to the user and are performed in addition to the 40 quality assurance inspections and tests to which every circuit is subjected before final seal. The tests, tabulated below for the specifier's convenience, are performed in accordance with the following conditions, sequence, and schedules on equipment calibrated to meet all requirements of MIL-Q-9858A and MIL-C-45662A.

Every circuit of every lot is processed to the environmental screens shown in Table I. These screens are performed in production and include 100% final production electrical test. Any unit failing either the environmental screens or the final production electrical tests is rejected and removed from the lot.

After completion of Table I tests, each manufacturing lot is sampled and tested by Quality Assurance for conformance to the requirements of Table II. The unsampled portion of the lot is held pending acceptance of the lot sample. Detailed electrical test limits and conditions applicable to each subgroup are shown in the Electrical Characteristics table of the individual part type data sheets.

Tables IIIA, IIIB, and IIIC provide a complete process qualification and verification program in accordance with the conditions of MIL-STD-883, Group A, B and C tests. These tests are performed once in every 90 day manufacturing period, on representative devices from each standard production die process family and on each production package family. The representative circuits and packages selected are changed routinely, and the tests performed monitor and qualify all structurally similar devices produced by the same process and production during that period. A summary of these test results is available on request at the time of order placement.

All of the applicable Electrical Parameters of Table IIIA are performed at pretest on the Table IIIC samples. This provides the MIL-STD-883 electrical parameter design verification Group A tests. These tests are performed on representative circuit types from every die process family type in manufacturing during this period.

Table IIIB consists of the package oriented qualification environmental stress tests of MIL-STD-883, Groups B and C. Representative samples from each package product family type are monitored and qualified every 90 day period by these tests. A common device is used as the die type for these packages and assembly qualification tests.

Table IIIC consists of the die process oriented qualification electrical stress or operational tests at high temperature per MIL-STD-883, Groups B and C. Representative devices from each die process family are monitored and qualified every 90 day period by these tests. The package type is randomly selected as applicable.

An additional screening series is available at extra cost. Details are given in Table V, MIL-STD-883, Method 5004, HIGH RELIABILITY SCREENING.

**TABLE I – SIGNETICS 100% PRODUCTION SCREEN TESTS**

TEST	CONDITIONS
Preseal Visual Thermal Shock	High Power—Low Power Liquid to Liquid, 5 Cycles, 60 Seconds at 0°C, 60 Seconds at 100°C, transfer time 5 seconds. (Note 1)
Centrifuge	Y1 Axis; 30,000 g minimum, 1 minute. (Note 1)
Hermeticity	Gross leak test (Bubble Test) (Note 1)
Production Electrical Tests	

**NOTE:**

1. Not applicable to solid molded packaged devices.

\*Systematic Uniformity and Reliability Evaluation

## SIGNETICS LINEAR SURE 883 PROGRAM

**TABLE II – SIGNETICS ACCEPTANCE TESTS** (Notes 2, 3)

SIGNETICS SUBGROUP	TEST	CONDITIONS	AQL	MIL-STD-105 INSPECTION LEVEL
A-1	Visual and Mechanical Inspection	MIL-STD-883 Method 2009	1.0%	II
A-2	DC Parameters	$T_A = +25^\circ\text{C}$	1.0%	II
A-7	DC End Point*	$T_A = +25^\circ\text{C}$	1.0%	II
A-4	DC Parameters	$T_A = +125^\circ\text{C}$	1.0%	II
A-5	DC Parameters	$T_A = -55^\circ\text{C}$	1.0%	II
A-6	AC Parameters	$T_A = +25^\circ\text{C}$	1.0%	II

\*Applies to Data Sheets Published After 6/11/70

**NOTES:**

- All test equipment calibrated to meet requirements of MIL-Q-9858A and MIL-C-45662A.
- Detailed tests, conditions, and limits applicable to each subgroup are given in the Signetics data sheet ELECTRICAL CHARACTERISTICS table. See Table IIIA for the Corresponding Group A tests of MIL-STD-883.

**TABLE IIIA – SIGNETICS MIL-STD-883 GROUP A ELECTRICAL TESTS**

MIL-STD-883 GROUP A SUBGROUP	SIGNETICS SUBGROUP	TEST DESCRIPTION
A1	A-2, A-7	Static tests at $25^\circ\text{C}$
A2	A-4	Static tests at maximum rated operating temperature
A3	A-5	Static tests at minimum rated operating temperature
A4	A-7	Dynamic tests at $25^\circ\text{C}$
A5	A-4	Dynamic tests at maximum rated operating temperature
A6	A-5	Dynamic tests at minimum rated operating temperature
A7		Functional tests at $25^\circ\text{C}$
A8		Functional tests at maximum and minimum rated operating temperature
A9	A-6	Switching tests at $25^\circ\text{C}$
A10		Switching tests at maximum rated operating temperature
A11		Switching tests at minimum rated operating temperature

**SIGNETICS LINEAR SURE 883 PROGRAM**

**TABLE IIIB – SIGNETICS MIL-STD-883 GROUPS B AND C ENVIRONMENTAL TESTS**

MIL-STD-883 GROUP B & C SUBGROUP	TEST DESCRIPTION	MIL-STD-883 METHOD	CONDITIONS	LTPD
B1	Physical Dimensions	2008	Test Condition A	15
B2	Marking Permanency	2008	Test Condition B, Para. 3, 2, 1	4 devices/no failures
	Visual and Mechanical	2008	Test Condition B	1 device/no failure
	Bond Strength	2011	Test Condition D, Para. 3, 7	15
B3	Solderability	2003	Solder Temperature 260°C ±10°C	15
B4	Lead Fatigue	2004	Test Condition B2	15
	Hermeticity	1014	Note 4	
	a. Fine		Test Condition A or B	
	b. Gross		Test Condition C	
C1	Pre-Test Electrical Parameters		Table IV as applicable	
	Thermal Shock	1011	15 Cycles. Test Condition C, +150°C to -65°C	15
	Temperature Cycle	1010	10 Cycles. Test Condition C, +150°C to -65°C	
	Hermeticity	1014	Note 4	
	a. Fine		Test Condition A or B	
	b. Gross		Test Condition C	
	Moisture Resistance	1004	Omit vibration and initial conditioning	
	End Point Electrical Parameters		Table IV as applicable	
	FAILURE CRITERIA		Refer to Table IV	
C2	Pre-Test Electrical Parameters		Table IV as applicable	
M	Mechanical Shock	2002	Test Condition B	15
	Vibration Variable Frequency	2007	Test Condition A	
	Constant Acceleration	2001		
	End Point Electrical Parameters		Table IV as applicable	
	FAILURE CRITERIA		Refer to Table IV	
C3	Salt Atmosphere	1009	Test Condition A. Omit initial conditioning	15
C4	Pre-Test Electrical Parameters		Table IV as applicable	
	High Temperature Storage	1008	T <sub>A</sub> = +150°C, t = 1000 hours	15
	End Point Electrical Parameters		Table IV as applicable	
	FAILURE CRITERIA		Refer to Table IV	

**NOTE:**

4. The Hermeticity tests are not employed for solid molded packages.

**TABLE IIIC – SIGNETICS MIL-STD-883 GROUPS B & C HIGH TEMPERATURE OPERATING LIFE TESTS**

MIL-STD-883 GROUP B & C SUBGROUP	TEST DESCRIPTION	MIL-STD-883 METHOD	CONDITIONS	LTPD
B5 & C5	Pre-Test and Design Verification Electrical Parameters		Table IIIA, as applicable, data sheet groups A & C	
	High Temperature Operating Life	1005	Test Condition B, T <sub>A</sub> = +125°C or +85°C, per Part Data Sheet t = 1008 hours	10
	End Point Electrical Parameters		Table IV as applicable	
	FAILURE CRITERIA		Refer to Table IV	

# SIGNETICS LINEAR SURE 883 PROGRAM

**TABLE IV – SIGNETICS FAILURE CRITERIA** (Note 5)

FUNCTION	PARAMETER	DELTA LIMITS
Operational Amplifier	Input Offset Voltage Open Loop Voltage Gain (Note 6)	±1mV Data Sheet Limits ±20%
Comparators	Input Offset Voltage Open Loop Gain	±1mV Data Sheet Limits
Sense Amplifiers	Input Threshold Voltage Input Bias Current	±1mV Data Sheet Limits ±30%
Video Amplifiers	Voltage Gain	±20% Data Sheet Limits
Voltage Regulators	Quiescent Current	±15%
RF/IF Amplifiers	Voltage Gain	±15% Data Sheet Limits
Phase Lock Loop	Center Frequency of Oscillation	±10% Initial Value

**NOTES:**

- 5. For limits of specific devices, consult Signetics Product Marketing
- 6. For 5709 only

## OPTIONAL HIGH RELIABILITY SCREENING

To maximize reliability in critical applications, the Optional High Reliability Screening of Table V provides for three levels of 100% screening of MIL-STD-883, Method 5004 at extra cost. This series eliminates the necessity for special specifications, minimizes cost and provides the shortest possible delivery time. This series is applied after the normal Group A acceptance test. Circuits subjected to this Pre-conditioning Series are clearly distinguishable from standard products in the following ways:

- (1) Individual serial number on each circuit (Class A only)

- (2) The first letters of a part number are either RA, RB, or RC  
 RA = Class A  
 RB = Class B  
 RC = Class C  
 i.e., RA5709G – 100% screening of Table V, Class A.
- (3) Individual device variables parametric test data is supplied with each shipment (Class A only).

Consult your local representative for price information. Device types should be specified with the appropriate letter prefixes.

TABLE V – SIGNETICS MIL-STD-883, METHOD 5004, HIGH RELIABILITY SCREENING

TEST	MIL-STD-883 METHOD	CLASS A	CLASS B	CLASS C	CLARIFICATIONS (Notes 7, 8, 9)
Internal Visual (pre-seal)	2010.1	Cond. A	Cond. B	Cond. B	Test Cond. A, Para. 3.1.1.7 delete the words "and parameter"
Stabilization Bake	1008 (24 hrs.)	Cond. C	Cond. C	Cond. C	Cond. C (150°C) max. for au/al metallization system. Cond. D (200°C) max. for al/al metallization system. No electrical measurements, at this point.
Thermal Shock	1011	Cond. A	Not Req'd	Not Req'd	Cond. C (150°C) max. for au/al metallization system. Cond. D (200°C) max. for al/al metallization system. No electrical measurements, no external visual inspection at this point.
Temperature Cycling	1010	Cond. C	Cond. C Note 7	Cond. C Note 7	(150°C) max. for au/al metallization Cond. D (200°C) max. for al/al metallization system. No electrical measurement, no external visual inspection, no hermeticity tests at this point.
Mechanical Shock	200, Y1 plane only	Cond. B	Not Req'd	Not Req'd	No electrical measurements at this point.
Centrifuge	2001	Cond. E Y2 then Y1 plane	Cond. E Y1 plane	Cond. E Y1 plane	
Hermeticity a. Fine Leak	1014, Note 6 (Hermetic devices only)	Cond. A or B	Cond. A or B	Cond. A or B	
b. Gross Leak		Cond. C	Cond. C	Cond. C	
Critical Electrical Parameters	Table IV as applicable	Read & Record	Not Req'd	Not Req'd	
Burn-In Test	1015, $T_A = +125^\circ\text{C}$	240 hrs. Cond. B	168 hrs. Cond. B	Not Req'd	
Critical Electrical Parameters	Table IV as applicable	Read & Record	Not Req'd	Not Req'd	
Signetics FAILURE CRITERIA		Table IV	Not Req'd	Not Req'd	
Reverse Bias Burn-In	1005, $T_A = +150^\circ\text{C}$ $t = 72$ hours	Cond. A or C	Not Req'd	Not Req'd	Not required unless specified on Purchase Order
Final Electrical Test	Perform go-no-go measurements of Signetics sub Group A Parameters	Signetics Sub Groups A-2, A-4 A-5, A-6	Signetics Sub Groups A-2, A-7	Signetics Sub Groups A-2, A-7	
Radiographic Inspection	2012	Yes	Req'd	Not Req'd	
External Visual	2009	Yes	Yes	Yes	

## NOTES:

7. Class B and Class C may be subjected to thermal shock as an alternate.
8. The test sequence of fine and gross leak may be reversed when fluorocarbons are utilized for gross leak.
9. The individual MIL-STD-883 Test Methods are, in many cases designed to "stand alone" as a sole screen or sole Group B environmental sampling test. But since 5004 specifies a screening series or flow, some of the measurements, etc., specified in an individual Test Method are not intended to be applicable in the screening series.

## SIGNETICS MOS 883 SURE PROGRAM

### QUALIFICATION AND SCREENING PROGRAM FOR MOS DEVICES

The Signetics SURE\*/883 Program consists of a combination of 100 percent and statistical sample tests designed to assure specified performance, continuing uniformity, and long term reliability of Signetics products. These tests are made regularly at no extra cost to the user and are performed in addition to the 40 quality assurance inspections and tests to which every circuit is subjected before final seal. The tests, tabulated below the specifier's convenience, are performed in accordance with the following conditions, sequence, and schedules on equipment calibrated to meet all requirements of MIL-Q-9858A and MIL-C-45662A.

Every circuit of every lot is processed to the environmental screens shown in Table I. These screens are performed in production and include 100% final production electrical test. Any unit failing either the environmental screens or the final production electrical tests is rejected and removed from the lot.

After completion of Table I tests, each manufacturing lot is sampled and tested by Quality Assurance for conformance to the requirements of Table II. The unsampled portion of the lot is held pending acceptance of the lot sample. Detailed test limits and conditions applicable to test group are shown in the Electrical Characteristics table of the individual part type data sheets.

Tables III, and IV provide a complete process qualification and verification program. These tests are performed once in every 90 day manufacturing period, on representative devices from each standard production die process family and on each production package family. The representative circuits and packages selected are changed routinely, and the tests performed monitor and qualify all structurally

similar devices produced by the same process and production during that period.

All of the applicable Electrical Parameters on the data sheets are performed at pretest on the Table IV samples. These tests are performed on representative circuit types from every die process family type in manufacturing during this period.

Table III consists of the Package oriented qualification environmental stress tests of MIL-STD-883, Groups B and C. Representative samples from each package product family type are monitored and qualified every 90 day period by these tests. A common device is used as the die type for these package and assembly qualification tests.

Table IV consists of the die process oriented qualification electrical stress or operational tests at high temperature. Representative devices from each die process are monitored and qualified every 90 day period by these tests. The package type is randomly selected as applicable.

**TABLE I — 100% PRODUCTION SCREEN TESTS**

TEST	CONDITIONS
Preseal Visual	High Power Low Power Liquid to Liquid
Thermal Shock	5 Cycles; 60 Seconds at 0°C, 60 Seconds at 100°C, Transfer Time 5 Seconds. Note 1.
Centrifuge	Y <sub>1</sub> Axis; 30,000 G Minimum 1 Minute. Note 1.
Hermeticity	Gross Leak Test (Bubble Test) Note 1.
Production Electrical Tests	AC and DC, T <sub>A</sub> = 25°C

NOTE:

1. Not applicable to solid molded packaged devices.

**TABLE II — SIGNETICS ACCEPTANCE TESTS (See Notes 2 and 3)**

TEST GROUP	CONDITIONS	AQL	MIL-STD-105 INSPECTION LEVEL
Visual and Mechanical Inspection	MIL-STD-883 Method 2009	1.0%	II
DC Parameters	T <sub>A</sub> = +25°C	1.0%	II
DC Parameters	T <sub>A</sub> = 70°C	1.0%	II
DC Parameters	T <sub>A</sub> = 0°C	1.0%	II
AC Parameters	T <sub>A</sub> = +25°C	1.0%	II

NOTES:

\*Systematic Uniformity and Reliability Evaluation

2. All test equipment calibrated to meet requirements of MIL-Q-9858A and MIL-C-45662A.
3. Detailed tests, conditions, and limits applicable to each test group are given in the Signetics data sheet ELECTRICAL CHARACTERISTICS table.



TABLE III – MIL-STD-833 GROUPS B AND C ENVIRONMENTAL TESTS

TEST DESCRIPTION	MIL-STD-833 METHOD	CONDITIONS	LTPD
Physical Dimensions	2008	Test Condition A	15
Marking Permanency	2008	Test Condition B, Para. 3.2.1	4 devices/no failures
Visual and Mechanical	2008	Test Condition B	1 device/no failures
Bond Strength	2011	Test Condition D, Para. 3.7	15
Solderability	2003	Solder Temperature 260°C ±10°C	15
Lead Fatigue	2004	Test Condition B <sub>2</sub>	15
Hermeticity	1014	Note 4	
a. Fine		Test Condition A or B	
b. Gross		Test Condition C	
Pre-Test Electrical Parameters		Table V as Applicable	
Thermal Shock	1011	15 Cycles. Test Condition C, +150°C to -65°C	15
Temperature Cycle	1010	10 Cycles. Test Condition C, +150°C to -65°C	
Hermeticity	1014	Note 4	
a. Fine		Test Condition A or B	
b. Gross		Test Condition C	
Moisture Resistance		Omit Vibration and Initial Conditioning	
End Point Electrical Parameters	1004	Table V as Applicable	
FAILURE CRITERIA		Refer to Table V	
Pre-Test Electrical Parameters		Table V as Applicable	
Mechanical Shock	2002	Test Condition B	15
Vibration Variable Frequency	2007	Test Condition A	
Constant Acceleration	2001		
End Point Electrical Parameters		Table V as Applicable	
FAILURE CRITERIA		Refer to Table V	
Salt Atmosphere	1009	Test Condition A. Omit Initial Conditioning.	
Pre-Test Electrical Parameters		Table V as Applicable	
High Temperature Storage	1008	T <sub>A</sub> = +150°C, t = 1000 hours	15
End Point Electrical Parameters		Table V as Applicable	
FAILURE CRITERIA		Refer to Table V	

NOTE:

4. The hermeticity tests are not employed for solid molded packages.

**SIGNETICS MOS 883 SURE PROGRAM**

**TABLE IV – HIGH TEMPERATURE OPERATING LIFE TESTS**

TEST DESCRIPTION	CONDITIONS	LTPD
Pre-Test Electrical Parameters	Refer to Table V	10
Operating Life Shift Registers ROMs, RAMs	$T_A = 70^\circ\text{C}$ ; $t = 1000$ hours Logic 1's Clocked Through Register Addresses Being Counted Through in a Binary Fashion	

**TABLE V – SIGNETICS FAILURE CRITERIA**

**SHIFT REGISTERS**

TEST	INPUT LEAKAGE	$I_{DD}$	$t_{ACCESS}$	"1" LEVELS	"0" LEVELS
Delta Limit	5X or 100nA whichever is greater	20%	Data Sheet Limits	20%	20%

**ROMs**

TEST	INPUT LEAKAGE	CLOCK LEAKAGE	$I_{DD}$	"1" LEVELS	"0" LEVELS
Delta Limit	5X or 100nA whichever is greater	5X or 100nA whichever is greater	20%	20%	20%

**RAMs**

TEST	INPUT LEAKAGE	$t_{ACCESS}$	$t_{REFRESH}^*$	"1" LEVELS	"0" LEVELS
Data Limit	5X or 100nA whichever is greater	Data Sheet Limit	Data Sheet Limits	20%	20%

\*For dynamic memories.

INDUSTRY CROSS REFERENCE GUIDE

AMD	SIGNETICS	PAGE
LM202	LM101T	6-207
LM101A	LM101AT	6-197
LM108	LM108T	6-217
LM111H	LM111T	6-230
LM201	LM201T	6-207
LM201D	LM201V	6-197
LM211H	LM211T	6-230
LM301A	LM301AT	6-197
LM301AD	LM301AV	6-197
LM307	LM307T	6-123
LM308	LM308T	6-217
LM311H	LM311T	6-245
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AM1402A	2502B	7-22
AM2071	82S07	4-17
AM2700	82S06	4-17
AM31L01	N8225	4-12

ANALOG DEVICES	SIGNETICS	PAGE
AD101AH	LM101AT	6-197
AD108H	LM108T	6-217
AD111N	LM111T	6-230
AD201H	LM201AT	6-197
AD211H	LM211T	6-230
AD301AH	LM301AT	6-197
AD308H	LM308T	6-217
AD311H	LM311T	6-245
AD710CN	$\mu$ A710CT	6-114
AD710CN	$\mu$ A710CA	6-114
AD710H	$\mu$ A710T	6-114
AD711CH	$\mu$ A711CK	6-116
AD711CN	$\mu$ A711CA	6-116
AD711H	$\mu$ A711K	6-116
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AD741CN	$\mu$ A741CA	6-131
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FAIRCHILD	SIGNETICS	PAGE
* $\mu$ A709	$\mu$ A709	6-112
* $\mu$ A710	$\mu$ A710	6-114
* $\mu$ A711	$\mu$ A711	6-116
* $\mu$ A741	$\mu$ A741	6-131
* $\mu$ A748	$\mu$ A748	6-140
3347	2518	7-75
9N00	S5400A/F	2-2
9N00	N7400A/F	2-2
9N01	S5401A/F	2-4
9N01	N7401A/F	2-4
9N02	S5402A/F	2-6
9N02	N7402A/F	2-6
9N03	S5403A/F	2-8
9N03	N7403A/F	2-8
9N04	S5404A/F	2-10
9N04	N7404A/F	2-10

FAIRCHILD	SIGNETICS	PAGE
9N05	S5405A/F	2-12
	N7405A/F	2-12
9N06	S5406A/F	2-14
	N7406A/F	2-14
9N07	S5407A/F	2-16
	N7407A/F	2-16
9N08	S5408A/F	2-18
	N7408A/F	2-18
9N09	N7409A/F	2-20
9N10	S5410A/F	2-22
9N11	S5411A/F	2-24
	N7411A/F	2-24
9N20	S5420A/F	2-28
	N7420A/F	2-28
9N26	S5426A/F	2-32
9N30	S5430A/F	2-34
	N7430A/F	2-34
9N40	S5440A/F	2-40
	N7440A/F	2-40
9N50	S5450A/F	2-60
	N7450A/F	2-60
9N51	S5451A/F	2-60
	N7451A/F	2-60
9N53	S5453A/F	2-62
	N7453A/F	2-62
9N54	S5454A/F	2-62
	N7454A/F	2-62
9N60	S5450A/F	2-60
	N7460A/F	2-66
9N70	S5470A/F	2-68
	N7470A/F	2-68
9N72	S547sA/F	2-70
	N747sA/F	2-70
9N73	S5473A/F	2-72
	N7473A/F	2-72
9N74	S5474A/F	2-74
	N7474A/F	2-74
9N76	S5476B/F	2-79
	N7476B/F	2-79
9N86	S5486B/F	2-90
	N7486A/F	2-90
9N107	S54107A/F	2-112
	N74107A/F	2-112
9H00	S54H00A/F	2-212
	N74H00A/F	2-212
9H01	S54H01A/F	2-214
	N74H01A/F	2-214
9H04	S54H04A/F	2-216
	N74H04A/F	2-216
9H05	S54H05A/F	2-218
	N74H05A/F	2-218
9H08	S54H08A/F	2-220
	N74H08A/F	2-220
9H10	S54H10A/F	2-222
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